Radiation Report

TPS7H4104-SP QMLP Total Ionizing Dose (TID) Report

ABSTRACT

This report discusses the total ionizing dose (TID) parametric results for the Texas Instruments TPS7H4104-SP, 3V to 7V input, 3A per channel, quad channel, peak- current mode, synchronous buck converter. The study was done to determine TID effects under high dose rate (HDR) and low dose rate (LDR) up to 100krad(Si). The results show that all samples passed within the specified limits up to 100krad(Si) for both HDR and LDR.

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1 Device Information

1.1 Product Description

The TPS7H4104-SP is an integrated, 7V, 3A per channel, quad channel, peak- current mode, synchronous buck converter designed for use in area sensitive, space environment applications. The device incorporate four identical channels that can be used to step down the power input voltage (PVIN) into four independent voltages up to 3A per phase or interleaved to increment the output current as needed, up to 12A.

Each channel incorporate the high and low side power MOSFETs with programmable soft-start and slope compensation. In addition per channel powergood flag, and enable signals are provided. The TPS7H4104 also incorporates and input (EN_SEQ) to create a sequential power up and reverse sequence down.

Cycle-by-cycle current limiting on the high-side FET protects the device in overload situations and is enhanced by a low-side sourcing and sinking current protection which prevents current runaway. Thermal shutdown disables the device when the die temperature exceeds thermal limit.

The TPS7H4104-SP is packaged in a 64-pin HTQFP plastic package. A standard microcircuit drawing (SMD) is available for the QML variant, 5962R2320801PYE.

1.2 Device Details

Table 1-1 lists the device information used in this TID HDR and LDR characterization.

Table 1-1. Device and Exposure Details

TID Exposure Details	
TI Device	TPS7H4104-SP
TI Part Name	5962R2320801PYE
Package	64-pin HTQFP (PAP)
Technology	LBC7
Lot Accept/Reject	All levels tested and passed up to 100krad(Si)
HDR Radiation Facility	Texas Instruments, Dallas, TX
HDR Dose Level	30krad(Si), 50krad(Si), 100krad(Si)
HDR Dose Rate	172rads(Si)/s
HDR Radiation Source	Gammacell (Hopewell, GR420) Co-60
LDR Radiation Facility	Radiation Test Solutions, Colorado Springs, Colorado
LDR Dose Level	50krad(Si), 100krad(Si)
LDR Dose Rate	10mrad(Si)/s ionizing radiation with increments
Irradiation and Test Temperature	Ambient, room temperature controlled to 25°C ±6°C per MIL-STD-883 and MILSTD-750

Figure 1-1. TPS7H4104-SP QMLP Device

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2 Total Dose Test Setup

2.1 Test Overview

The TPS7H4104-SP was tested according to MIL-STD-883, Test Method 1019.9. For the HDR testing, Condition A and for the LDR testing, Condition D, were used. The product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices remained functional passing all parametric test limits.

2.2 Test Description and Facilities

The TPS7H4104-SP HDR exposure was performed on biased and unbiased devices in a Co-60 gamma cell at the TI facility in Dallas, Texas. The unattenuated dose rate of this cell is 172.681rads(Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and full post-radiation electrical evaluation using Texas Instruments ATE was conducted. ATE test limits are set per data sheet electrical limits based on qualification and characterization data. Post-radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under HDR and LDR exposures were tested in two conditions (biased and unbiased) as described in the following sections.

2.3.1 Unbiased

For the unbiased HDR and LDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2-1 shows the diagram for HDR and LDR exposures with biased condition.

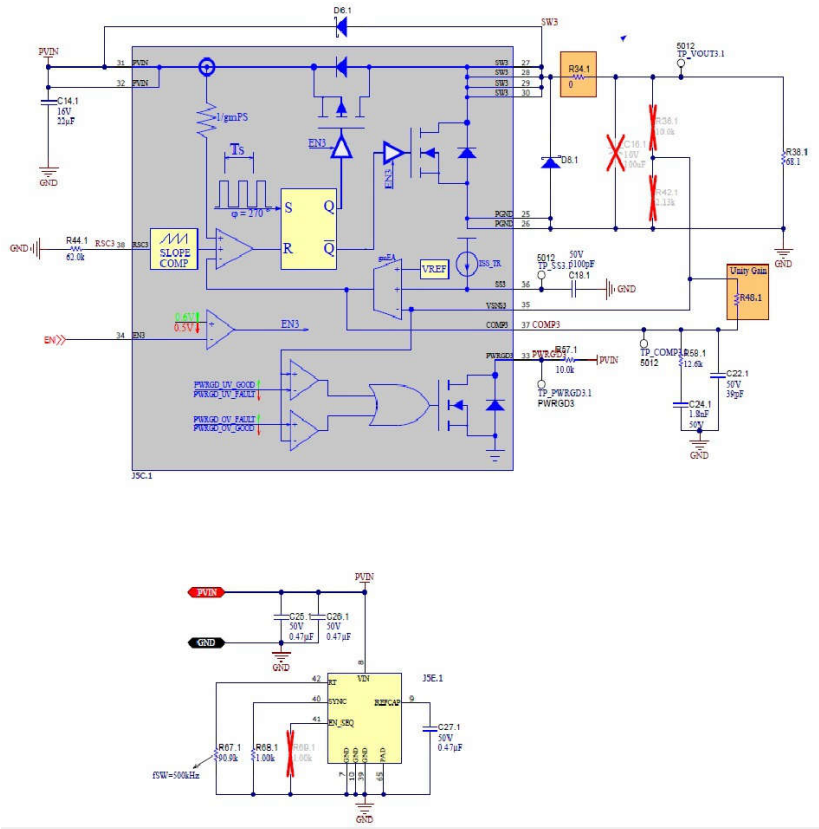

Figure 2-1. Bias Diagram Used in TID Exposures

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2.4 Test Configuration and Condition

HDR devices were stressed at 30krad (Si), 50krad (Si), and 100krad (Si) for biased and unbiased conditions. LDR devices were stressed at 50krad (Si) and 100krad (Si) for biased and unbiased conditions.

Table 2-1. HDR: 30krad (Si), 50krad (Si), and 100krad (Si) Biased Device Information

Total Samples: 15		
Exposure Levels		
30krad (Si)	50krad (Si)	100krad (Si)
16, 17, 18, 19, 20	40, 41, 42, 43, 44	50, 51, 52, 53, 54

Table 2-2. LDR: 50krad (Si) and 100krad (Si) Biased Device Information

Total Samples: 10	
Exposure Levels	
50krad (Si)	100krad (Si)
17, 18, 19, 20, 21	29, 30, 31, 32, 34

Table 2-3. HDR: 30krad (Si), 50krad (Si) and 100krad (Si) Unbiased Device Information

Total Samples: 15		
Exposure Levels		
30krad (Si)	50krad (Si)	100krad (Si)
11, 12, 13, 14, 15	30, 31, 32, 33, 34	45, 46, 47, 48, 49

Table 2-4. LDR: 50krad (Si) and 100krad (Si) Unbiased Device Information

Total Samples: 10	
Exposure Levels	
50krad (Si)	100krad (Si)
11, 12, 13, 14, 15	24, 25, 26, 27, 28

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3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The parametric data for the TPS7H4104-SP passes up to 100krad(Si) HDR and LDR TID irradiation. The drifts of the electrical parameters through HDR and LDR were within the data sheet limits.

Overall, the TPS7H4104-SP showed a strong degree of hardness to HDR and LDR TID irradiation up to 100krad(Si) for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. The parameters that showed a greater degree of change between pre- and post-irradiation were still within the electrical performance characteristics specified in the data sheet electrical parameters. See *TPS7H4104-SP Radiation-Hardeness-Assured, 3V to 7V Input , 3A/Channel, Quad Channel Synchronous Step Down Converter* for the data sheet electrical parameters and associated tests.

See Appendix A for the HDR report up to 100krad(Si).

See Appendix B for the LDR report up to 100krad(Si).

3.2 Specification Compliance Matrix

Over 3V ≤ VIN ≤ 7V, PVINx = VIN, REFCAP = 470nF, open loop configuration, over operating temperature range T_A = –55°C to 125°C, typical values are at T_A = 25°C, valid for all 4 phases, unless otherwise noted; includes Group E radiation testing at T_A= 25°C.

Table 3-1. Specification Compliance Matrix

Parameter		Test Conditions	MIN	TYP	MAX	UNIT	Test Number
POWER SUPPLIES AND CURRENTS							
V_{UVLOR_VIN}	VIN internal UVLO rising threshold	I_{OUTx} = 0A, V_{ENx} = 1V, PVIN = 5V	2.63	2.7	2.83	V	42.13 to 42.16
V_{UVLOF_VIN}	VIN internal UVLO falling threshold	I_{OUTx} = 0A, V_{ENx} = 1V, PVIN = 5V	2.47	2.52	2.60		42.17 to 42.20
V_{UVLOR_PVIN}	PVIN internal UVLO rising threshold	I_{OUTx} = 0A, V_{ENx} = 1V, VIN = 5V	2.39	2.44	2.58		42.1 to 42.4
V_{UVLOF_PVIN}	PVIN internal UVLO falling threshold	I_{OUTx} = 0A, V_{ENx} = 1V, VIN = 5V	1.97	2	2.11		42.5 to 42.8
I_{SHDN_VIN}	VIN shutdown supply current	V_{ENx} = 0V		6	8.5	mA	18.1, 19.1
I_{SHDN_PVIN}	PVIN shutdown supply current	V_{ENx} = 0V		2.27	4.3		18.2, 19.2
I_{Q_VIN}	VIN operating quiescent current (non switching)	V_{ENx} = 7V, VSNSx = 1V		6.67	15		18.3, 19.3
I_{Q_PVIN}	PVIN operating quiescent current (non switching)	V_{ENx} = 7V, VSNSx = 1V		2.1	3.7		18.4, 19.4
ENABLE and EN_SEQ							
V_{ENx_RISING}	Enable rising threshold (turn-on)	PVINx = VIN = 5V	0.573	0.606	0.635	V	33.1 to 33.4 and 34.1 to 34.4
$V_{ENx_FALLING}$	Enable falling threshold (turn-off)	PVINx = VIN = 5V	0.473	0.500	0.532		33.5 to 33.8 and 34.5 to 34.8
$V_{EN_SEQ_RISING}$	Enable sequence rising threshold (sequence up)	Rise time ≥ 100ns		71%	80%	× VIN	54.2
$V_{EN_SEQ_FALLING}$	Enable sequence falling threshold (sequence down)	Fall time ≤ 100ns	17%	25%			54.3
V_{CHx_ON}	Sequence UP deemed good voltage			87.4%		× V_{REFx}	55.1 to 55.3 and 56.1 to 56.3
V_{CHx_OFF}	Sequence DOWN deemed no-good voltage			15.4%			55.4 to 55.6 and 56.4 to 56.6
$t_{ENx_VIN_RISING_PD}$	Enable propogation delay when ENx and VIN are tied together.	VIN=ENx high to SW high		0.85	1.7	ms	35.1 to 35.4 and 36.1 to 36.4

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Table 3-1. Specification Compliance Matrix (continued)

Parameter		Test Conditions		MIN	TYP	MAX	UNIT	Test Number
$t_{ENx_RISING_PD}$	Enable propogation delay	ENx high to SW high when VIN>V_{UVLOR_VIN} for at least 1.7ms			50	100	µs	35.5 to 35.8 and 36.5 to 36.8
$t_{ENx_FALLING_PD}$	Disabled propagation delay	ENx low to SW high impedance			9.5	35		35.9 to 35.12 and 36.9 to 36.12
I_{ENx_LKG}	Enable input leakage current	V_{ENx} = 7V			0.05	154	nA	34.13 to 34.16
VOLTAGE REFERENCE								
V_{REFx}	Internal voltage reference (including error amplifier V_{IOx})		T_A = 25℃	592.44	599.44	604.34	mV	21.2 to 21.5 and 22.2 to 22.5
V_{REFCAP}	REFCAP voltage			1.2	1.235	1.248	V	21.1, 22.1
ERROR AMPLIFIER								
I_{VSNSx_LKG}	VSNSx input leakage current	VSNSx = 600mV, V_{COMP} = 1V				30	nA	38.1 to 38.4 and 39.1 to 39.4
gm_{EAx}	Error amplifier transconductance	–10µA < I_{COMP} < 10µA, V_{COMP} = 1V	T_A = 25℃	1153	1672	2191	µS	38.5 to 38.8; 38.17 to 38.20; 39.5 to 39.8; and 39.17 to 39.20
EA_{x_ISRC}	Error amplifier source	V_{COMP} = 1V, ± 100mV input overdrive		88	137	200	µA	38.9 to 38.12 and 39.9 to 39.12
EA_{x_ISNK}	Error amplifier sink			87	135	200		38.13 to 38.16 and 39.13 to 39.16
gm_{PSx}	Power stage transconductance	V_{COMPx} = 500mV		5.78	8.35	10.46	S	68.17 to 68.20 and 69.17 to 69.20
$gm_{PSx_MATCHING}$	Power stage transconductance matching across all phases	V_{COMPx} = 500mV			1%			68.21 to 68.24 and 69.21 to 69.24
OVERCURRENT PROTECTION								
I_{OC_HSx}	High-side switch overcurrent threshold	Slew rate = 25mA/µs		5.0	5.6	6.3	A	26.2 to 26.5 and 27.2 to 27.5
$I_{OC_LS_SOURCINGx}$	Low-side switch overcurrent sourcing threshold			4.39	6	7.6	A	28.2 to 28.5; 29.2 to 29.5: and 77.2 to 77.5
$I_{OC_LS_SINKINGx}$	Low-side switch overcurrent sinking threshold			1.5	2.55	3.9	A	28.6 to 28.9; 29.6 to 29.9; and 77.6 to 77.9
$COMPx_{CLAMP}$	COMP voltage clamp			1.7	1.9	2.13	V	40.13 to 40.16 and 41.13 to 41.16
SOFT START AND TRACKING								
I_{SS_TRx}	Soft start charge current	V_{SS_TRx} ≥ 90mV		1.4	2.31	2.83	µA	40.1 to 40.4 and 41.1 to 41.4
$R_{SS_TRx_DISCHARGE}$	Soft start discharge pull-down resistor	V_{SS_TRx} = 110mV		230	376	513	Ω	40.5 and 40.8 and 41.5 to 41.8
$SS_TRx_{START_UP}$	Maximum voltage on SS before startup				22	50	mV	40.9 to 40.12 and 41.9 to 41.12

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Table 3-1. Specification Compliance Matrix (continued)

Parameter		Test Conditions		MIN	TYP	MAX	UNIT	Test Number
MINIMUM ON, OFF, AND DEAD TIME								
t_{ONx_MIN}	Minimum on time	10% of rising edge to 90% of falling edge of V_{SWx}, I_{OUT} = 400mA	VIN = 3V		163	260	ns	45.1 to 45.4
			VIN = 5V		182	270		46.1 to 46.4
			VIN = 7V		216	320		47.1 to 47.4
SWITCHING FREQUENCY AND SYNCHRONIZATION								
t_{SYNC_DLY}	SYNC to SW delay	V_{IN} = 3V			221	314	ns	72.13 to 72.16
t_{SYNC_DLY}	SYNC to SW delay	V_{IN} = 5V			194	234	ns	73.1 to 73.4
t_{SYNC_DLY}	SYNC to SW delay	V_{IN} = 7V			184	234	ns	74.13 to 74.16
V_{SYNC_VIH}	SYNC input high	V_{IN} = 3V		1.4			V	72.17
		V_{IN} = 5V		1.8				73.5
		V_{IN} = 7V		2				74.17
V_{SYNC_VIL}	SYNC input low					0.8	V	72.18, 74.18
$t_{CLK_E_I}$	External clock to internal clock detection time	RT populated			2	6	× T_{SYNC}	72.22 to 72.25 and 74.22 to 74.25
POWER GOOD								
$PWRGDx_{UV_FAULT}$	V_{SENSE} falling threshold (fault)			89%	91%	92%		30.5 to 30.8 and 31.5 to 31.8
$PWRGDx_{UV_GOOD}$	V_{SENSE} rising threshold (good)			92%	94%	96%		30.9 to 30.12 and 31.9 to 31.12
$PWRGDx_{OV_FAULT}$	V_{SENSE} rising threshold (fault)			107%	109%	111%		30.13 to 30.16 and 31.13 to 31.16
$PWRGDx_{OV_GOOD}$	V_{SENSE} falling threshold (good)			104%	106%	108%		30.17 to 30.20 and 31.17 to 31.20
I_{PWRGDx_LKG}	Output open high leakage	V_{SENSEx} = V_{REFx} , V_{PWRGD} = 7V			2	20	nA	31.21 to 31.24
V_{PWRGDx_VOL}	Power good output low	I_{PWRGD_SINK} ≤ 2mA			310	400	mV	30.1 to 30.4 and 31.1 to 31.4
VIN_{MIN_PWRGDx}	Minimum VIN for valid PWRGD output	Measured when V_{PWRGD} ≤ 0.5V at 100µA			0.6	1	V	30.25 and 30.28
MOSFET								
$R_{DS_ON_HSx}$	High-side switch resistance	PVIN = VIN = 3V, I_{OUTx} = 500mA	T_A = 25°C		70	88	mΩ	48.1 to 48.4
		PVIN = VIN = 5V, I_{OUTx} = 500mA	T_A = 25°C		62	80		49.1 to 49.4
		PVIN = VIN = 7V, I_{OUTx} = 500mA	T_A = 25°C		59	76		50.1 to 50.4
$R_{DS_ON_LSx}$	Low-side switch resistance	PVIN = VIN = 3V, I_{OUTx} = 500mA	T_A = 25°C		58	68	mΩ	51.1 to 51.4
		PVIN = VIN = 5V, I_{OUTx} = 500mA	T_A = 25°C		55	64		52.1 to 52.44
		PVIN = VIN = 7V, I_{OUTx}= 500mA	T_A = 25°C		54	63		53.1 to 53.4

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4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H4104-SP Radiation-Hardeness-Assured, 3V to 7V Input , 3A/Channel, Quad Channel Synchronous Step Down Converter*, datasheet

4.2 Reference Documents

Texas Instruments' total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

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A Appendix: HDR TID Report Data

This appendix contains the HDR TID report data.

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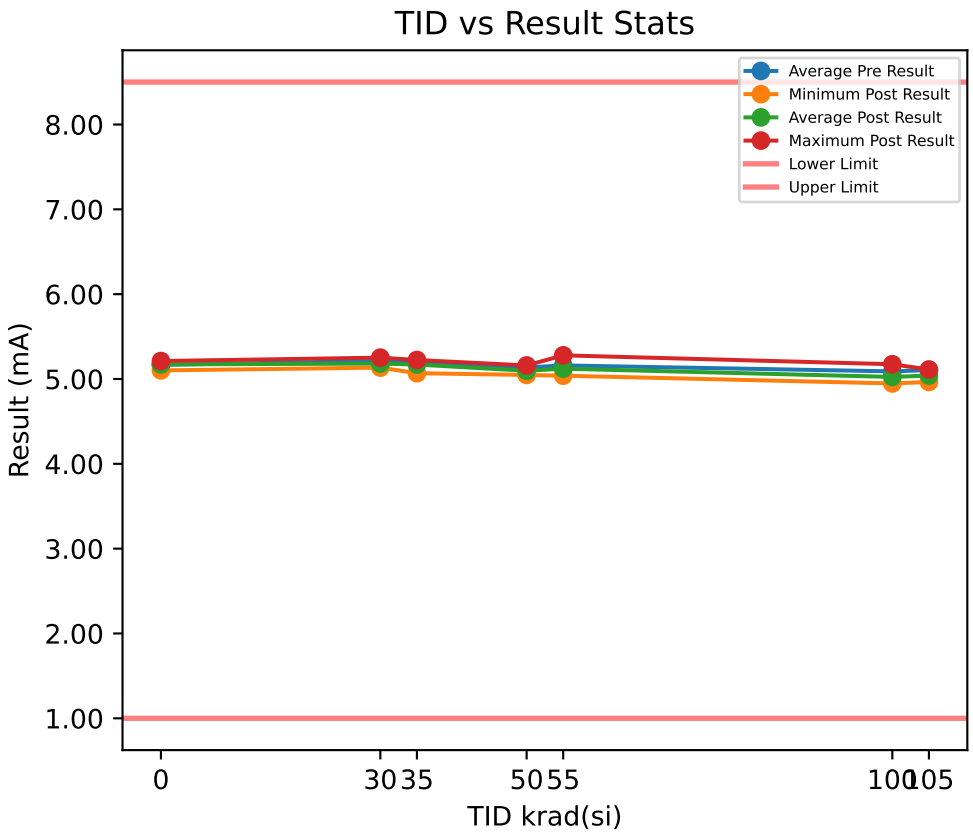
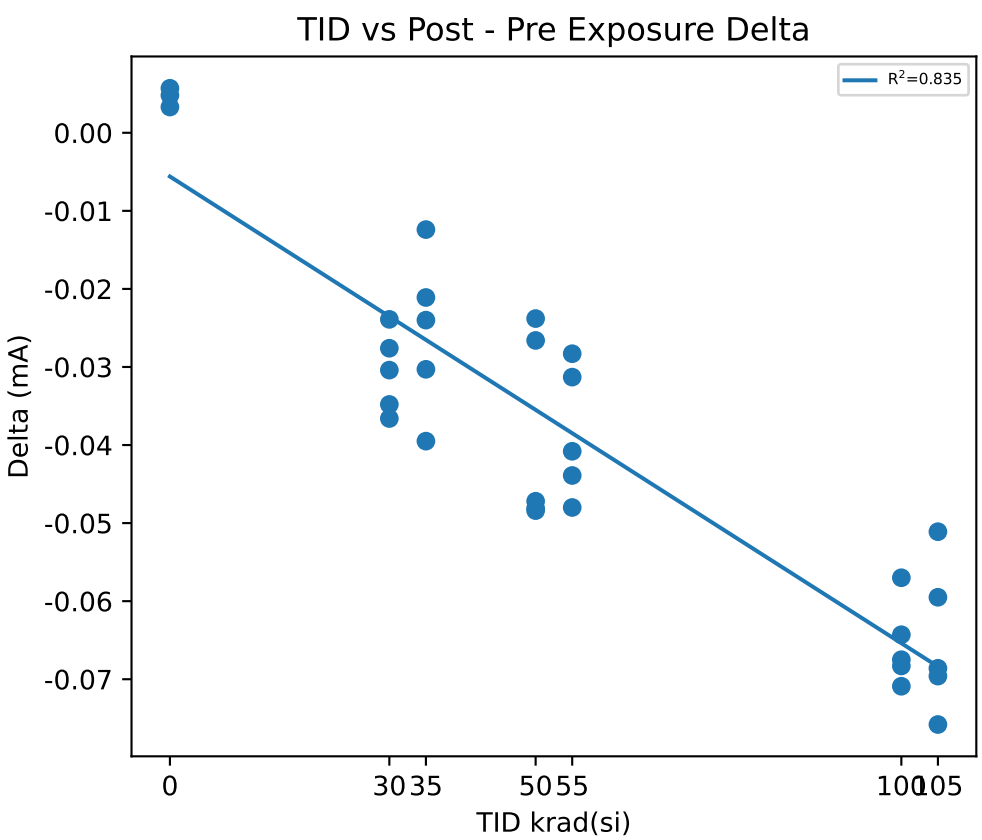
Device Test: 18.1 _IQ|ShutDown/VIN/3/3/0/0/90.9/634//1.8//pre/@VIN_SHDN_CURR





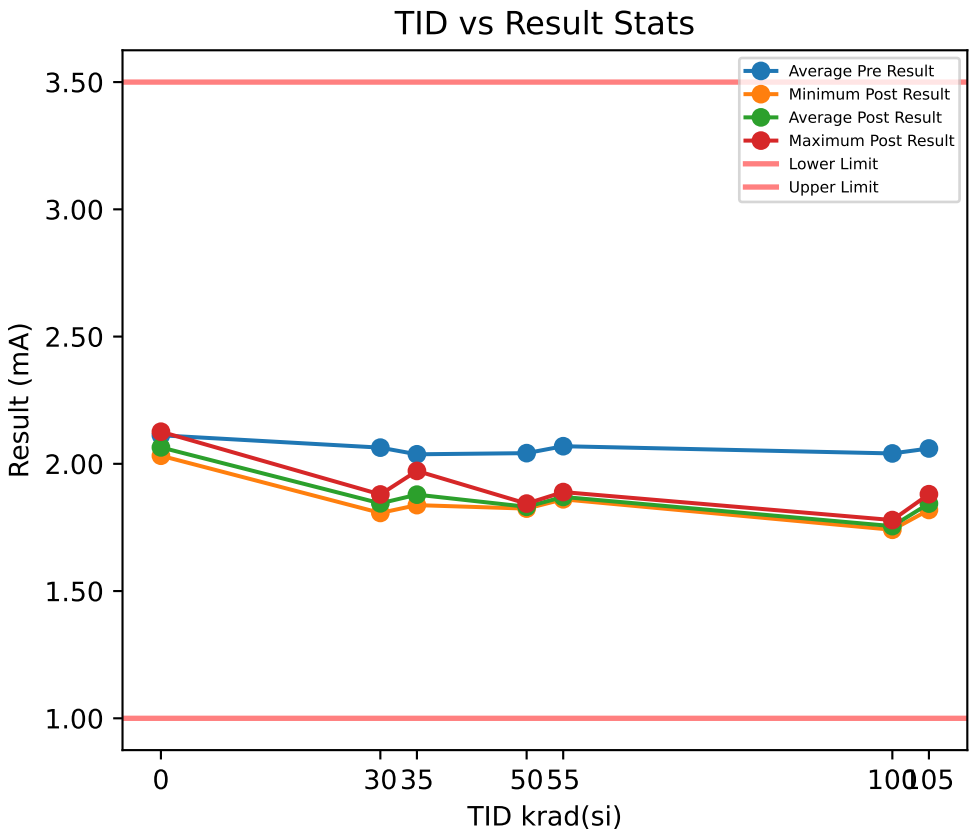
Test Results (Lower Limit = 1.0, Upper Limit = 8.5 (mA))

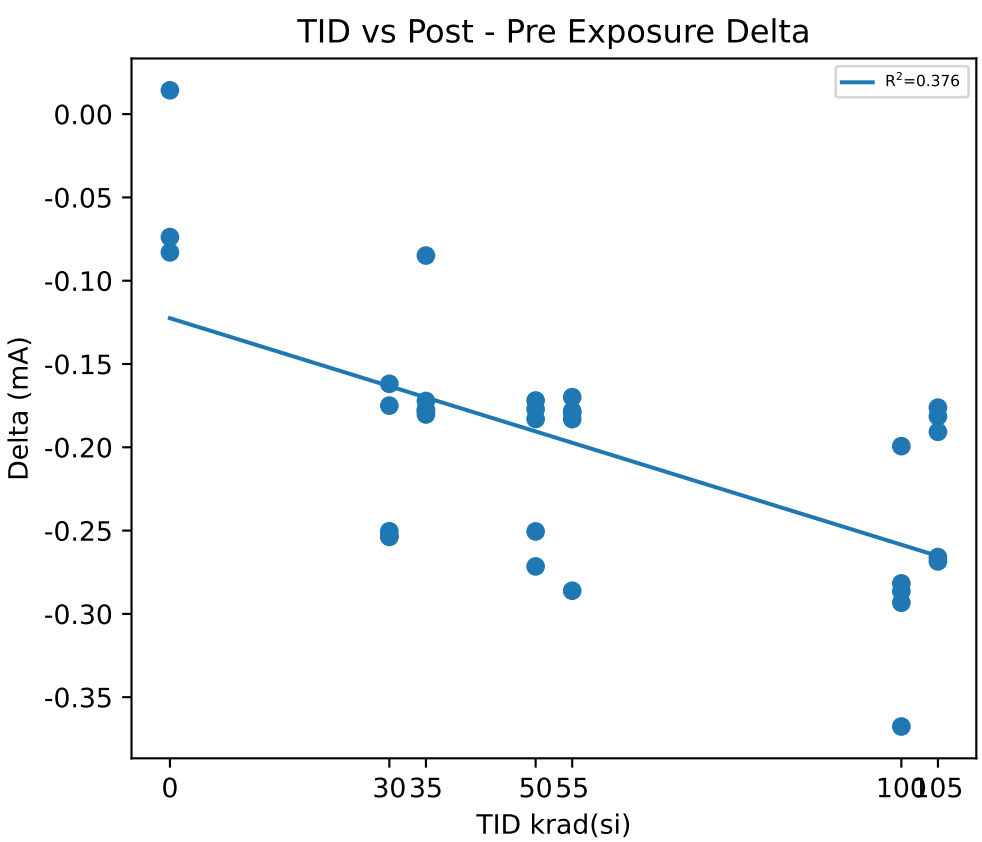
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.2069	5.2117	0.0048
2	0	CU2	5.0957	5.1014	0.0057
3	0	CU3	5.1988	5.2021	0.0033
11	30	Unbiased-30krad	5.2065	5.1826	-0.0239
12	30	Unbiased-30krad	5.2214	5.1848	-0.0366
13	30	Unbiased-30krad	5.2793	5.2517	-0.0276
14	30	Unbiased-30krad	5.1688	5.134	-0.0348
15	30	Unbiased-30krad	5.185	5.1546	-0.0304
16	35	Biased-30krad	5.217	5.1867	-0.0303
17	35	Biased-30krad	5.2362	5.2238	-0.0124
18	35	Biased-30krad	5.1905	5.1665	-0.024
19	35	Biased-30krad	5.2264	5.2053	-0.0211
20	35	Biased-30krad	5.1077	5.0682	-0.0395
30	50	Unbiased-50krad	5.1014	5.0776	-0.0238
31	50	Unbiased-50krad	5.1205	5.0721	-0.0484
32	50	Unbiased-50krad	5.0743	5.0477	-0.0266
33	50	Unbiased-50krad	5.2077	5.1596	-0.0481
34	50	Unbiased-50krad	5.1742	5.127	-0.0472
40	55	Biased-50krad	5.1416	5.1103	-0.0313
41	55	Biased-50krad	5.1735	5.1255	-0.048
42	55	Biased-50krad	5.3228	5.2789	-0.0439
43	55	Biased-50krad	5.0946	5.0538	-0.0408
44	55	Biased-50krad	5.0672	5.0389	-0.0283
45	100	Unbiased-100krad	5.0792	5.0222	-0.057
46	100	Unbiased-100krad	5.0151	4.9476	-0.0675
47	100	Unbiased-100krad	5.0583	4.99	-0.0683
48	100	Unbiased-100krad	5.238	5.1737	-0.0643
49	100	Unbiased-100krad	5.0584	4.9875	-0.0709
50	105	Biased-100krad	5.18	5.1114	-0.0686
51	105	Biased-100krad	5.0163	4.9652	-0.0511
52	105	Biased-100krad	5.0585	4.9827	-0.0758
53	105	Biased-100krad	5.0919	5.0324	-0.0595
54	105	Biased-100krad	5.1795	5.1099	-0.0696

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0957	5.1671	5.2069	0.061996	5.1014	5.1717	5.2117	0.061099	0.0033	0.0046	0.0057	0.0012124
30	5.1688	5.2122	5.2793	0.042553	5.134	5.1815	5.2517	0.044497	-0.0366	-0.03066	-0.0239	0.0051854
35	5.1077	5.1956	5.2362	0.051979	5.0682	5.1701	5.2238	0.060817	-0.0395	-0.02546	-0.0124	0.010152
50	5.0743	5.1356	5.2077	0.054414	5.0477	5.0968	5.1596	0.045402	-0.0484	-0.03882	-0.0238	0.01248
55	5.0672	5.1599	5.3228	0.099892	5.0389	5.1215	5.2789	0.095292	-0.048	-0.03846	-0.0283	0.0083751
100	5.0151	5.0898	5.238	0.086072	4.9476	5.0242	5.1737	0.087662	-0.0709	-0.0656	-0.057	0.0053535
105	5.0163	5.1052	5.18	0.073104	4.9652	5.0403	5.1114	0.068774	-0.0758	-0.06492	-0.0511	0.009672

Device Test: 18.2 _IQ|ShutDown/PVIN/3/3/0/0/90.9/634//1.8//pre/@PVIN_SHDN_CURR





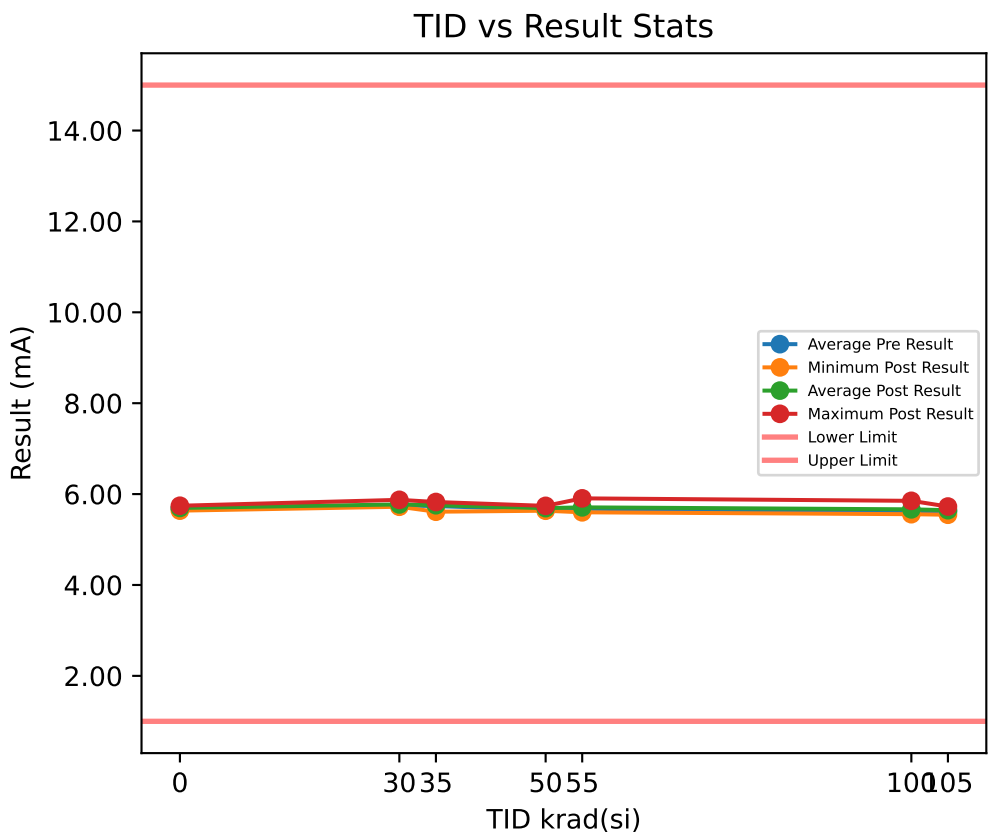
Test Results (Lower Limit = 1.0, Upper Limit = 3.5 (mA))

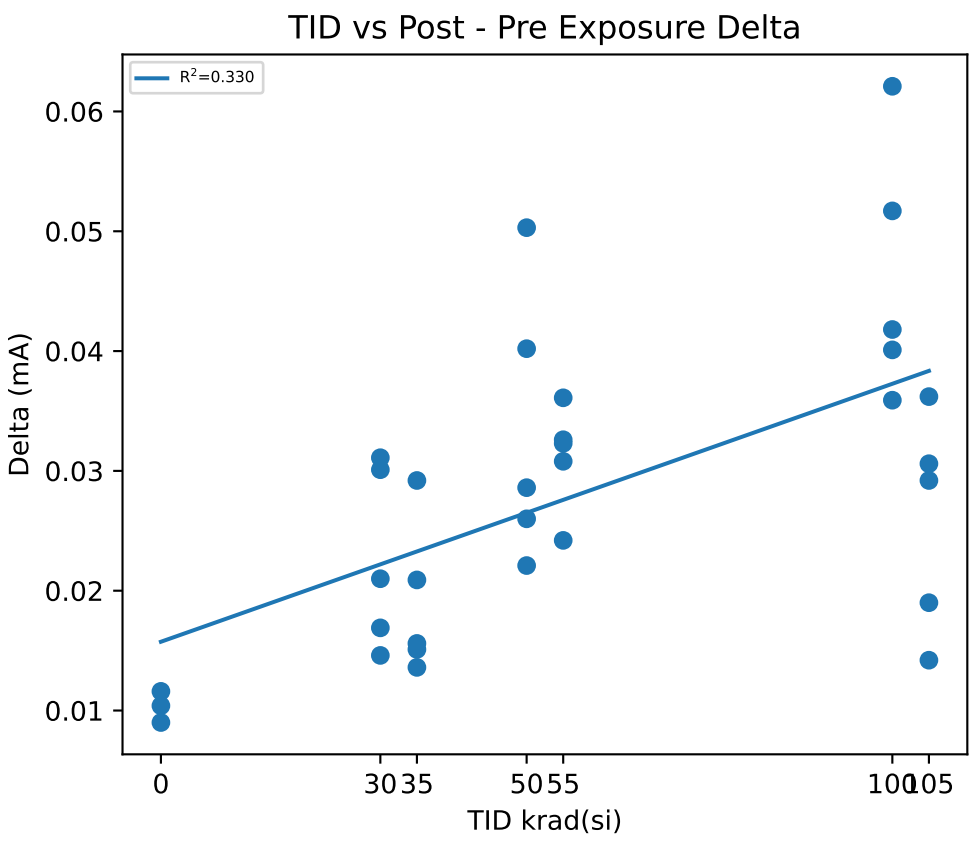
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0214	2.0357	0.0143
2	0	CU2	2.1148	2.0318	-0.083
3	0	CU3	2.2	2.1262	-0.0738
11	30	Unbiased-30krad	1.9988	1.8369	-0.1619
12	30	Unbiased-30krad	2.1117	1.8613	-0.2504
13	30	Unbiased-30krad	2.0137	1.8387	-0.175
14	30	Unbiased-30krad	2.0604	1.807	-0.2534
15	30	Unbiased-30krad	2.1334	1.8796	-0.2538
16	35	Biased-30krad	2.0151	1.8377	-0.1774
17	35	Biased-30krad	2.0302	1.852	-0.1782
18	35	Biased-30krad	2.1443	1.9721	-0.1722
19	35	Biased-30krad	1.9683	1.8834	-0.0849
20	35	Biased-30krad	2.0293	1.849	-0.1803
30	50	Unbiased-50krad	2.011	1.828	-0.183
31	50	Unbiased-50krad	2.1036	1.8321	-0.2715
32	50	Unbiased-50krad	1.9998	1.8279	-0.1719
33	50	Unbiased-50krad	2.0208	1.8437	-0.1771
34	50	Unbiased-50krad	2.0745	1.824	-0.2505
40	55	Biased-50krad	2.1466	1.8605	-0.2861
41	55	Biased-50krad	2.0684	1.889	-0.1794
42	55	Biased-50krad	2.0528	1.8746	-0.1782
43	55	Biased-50krad	2.032	1.8621	-0.1699
44	55	Biased-50krad	2.0461	1.863	-0.1831
45	100	Unbiased-100krad	1.9544	1.7551	-0.1993
46	100	Unbiased-100krad	2.0341	1.7408	-0.2933
47	100	Unbiased-100krad	2.035	1.7486	-0.2864
48	100	Unbiased-100krad	2.1198	1.7522	-0.3676
49	100	Unbiased-100krad	2.0607	1.779	-0.2817
50	105	Biased-100krad	2.0331	1.8517	-0.1814
51	105	Biased-100krad	2.0568	1.8806	-0.1762
52	105	Biased-100krad	2.1054	1.8395	-0.2659
53	105	Biased-100krad	2.0094	1.8187	-0.1907
54	105	Biased-100krad	2.0967	1.8282	-0.2685

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0214	2.1121	2.2	0.089331	2.0318	2.0646	2.1262	0.053412	-0.083	-0.0475	0.0143	0.053718
30	1.9988	2.0636	2.1334	0.058917	1.807	1.8447	1.8796	0.027439	-0.2538	-0.2189	-0.1619	0.046305
35	1.9683	2.0374	2.1443	0.06484	1.8377	1.8788	1.9721	0.054821	-0.1803	-0.1586	-0.0849	0.041307
50	1.9998	2.0419	2.1036	0.044839	1.824	1.8311	1.8437	0.0075831	-0.2715	-0.2108	-0.1719	0.046589
55	2.032	2.0692	2.1466	0.045216	1.8605	1.8698	1.889	0.01208	-0.2861	-0.19934	-0.1699	0.04874
100	1.9544	2.0408	2.1198	0.059541	1.7408	1.7551	1.779	0.014373	-0.3676	-0.28566	-0.1993	0.05968
105	2.0094	2.0603	2.1054	0.040932	1.8187	1.8437	1.8806	0.024023	-0.2685	-0.21654	-0.1762	0.046546

Device Test: 18.3 _IQ|ActiveHSoffLSon/VIN/3/3/0/0/90.9/634//1.8//pre/@IQ_VIN





Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

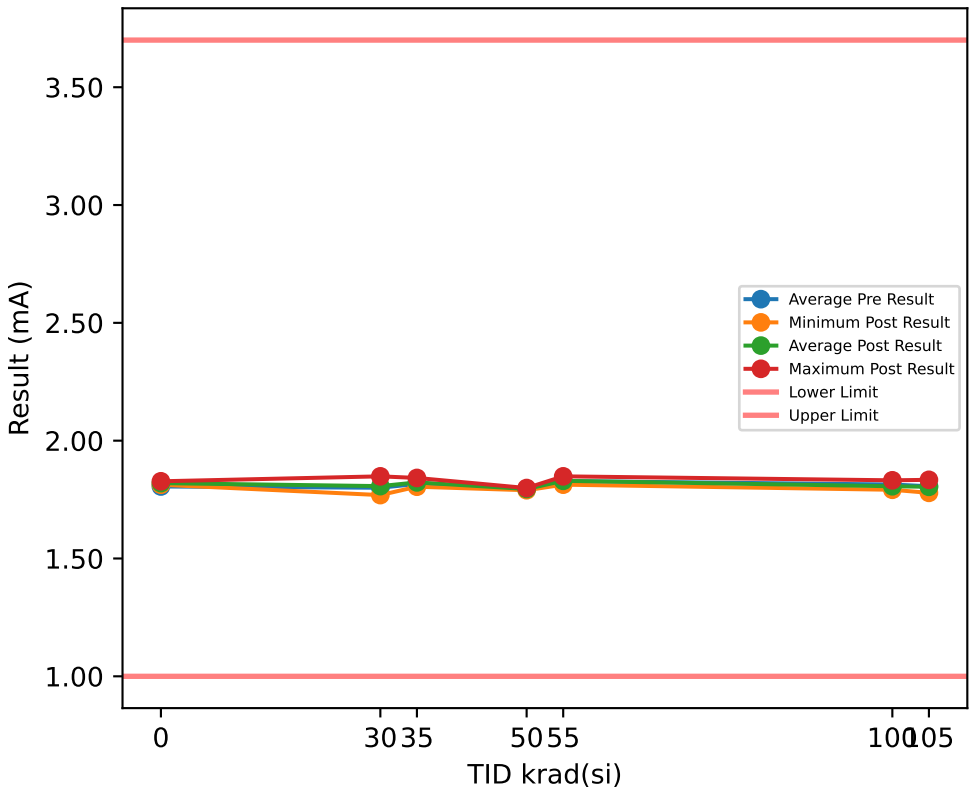
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7329	5.7433	0.0104
2	0	CU2	5.6241	5.6357	0.0116
3	0	CU3	5.6985	5.7075	0.009
11	30	Unbiased-30krad	5.7317	5.7486	0.0169
12	30	Unbiased-30krad	5.7792	5.7938	0.0146
13	30	Unbiased-30krad	5.8434	5.8735	0.0301
14	30	Unbiased-30krad	5.695	5.7261	0.0311
15	30	Unbiased-30krad	5.7003	5.7213	0.021
16	35	Biased-30krad	5.7581	5.7732	0.0151
17	35	Biased-30krad	5.7727	5.8019	0.0292
18	35	Biased-30krad	5.7406	5.7615	0.0209
19	35	Biased-30krad	5.8101	5.8257	0.0156
20	35	Biased-30krad	5.5986	5.6122	0.0136
30	50	Unbiased-50krad	5.6473	5.6976	0.0503
31	50	Unbiased-50krad	5.6353	5.6639	0.0286
32	50	Unbiased-50krad	5.5937	5.6339	0.0402
33	50	Unbiased-50krad	5.7186	5.7407	0.0221
34	50	Unbiased-50krad	5.6917	5.7177	0.026
40	55	Biased-50krad	5.6615	5.6976	0.0361
41	55	Biased-50krad	5.696	5.7202	0.0242
42	55	Biased-50krad	5.8736	5.9059	0.0323
43	55	Biased-50krad	5.5872	5.618	0.0308
44	55	Biased-50krad	5.5664	5.599	0.0326
45	100	Unbiased-100krad	5.6248	5.6649	0.0401
46	100	Unbiased-100krad	5.506	5.5577	0.0517
47	100	Unbiased-100krad	5.5824	5.6242	0.0418
48	100	Unbiased-100krad	5.7894	5.8515	0.0621
49	100	Unbiased-100krad	5.5886	5.6245	0.0359
50	105	Biased-100krad	5.7117	5.7259	0.0142
51	105	Biased-100krad	5.5151	5.5457	0.0306
52	105	Biased-100krad	5.5796	5.5986	0.019
53	105	Biased-100krad	5.5996	5.6358	0.0362
54	105	Biased-100krad	5.6922	5.7214	0.0292

Test Statistics (mA)

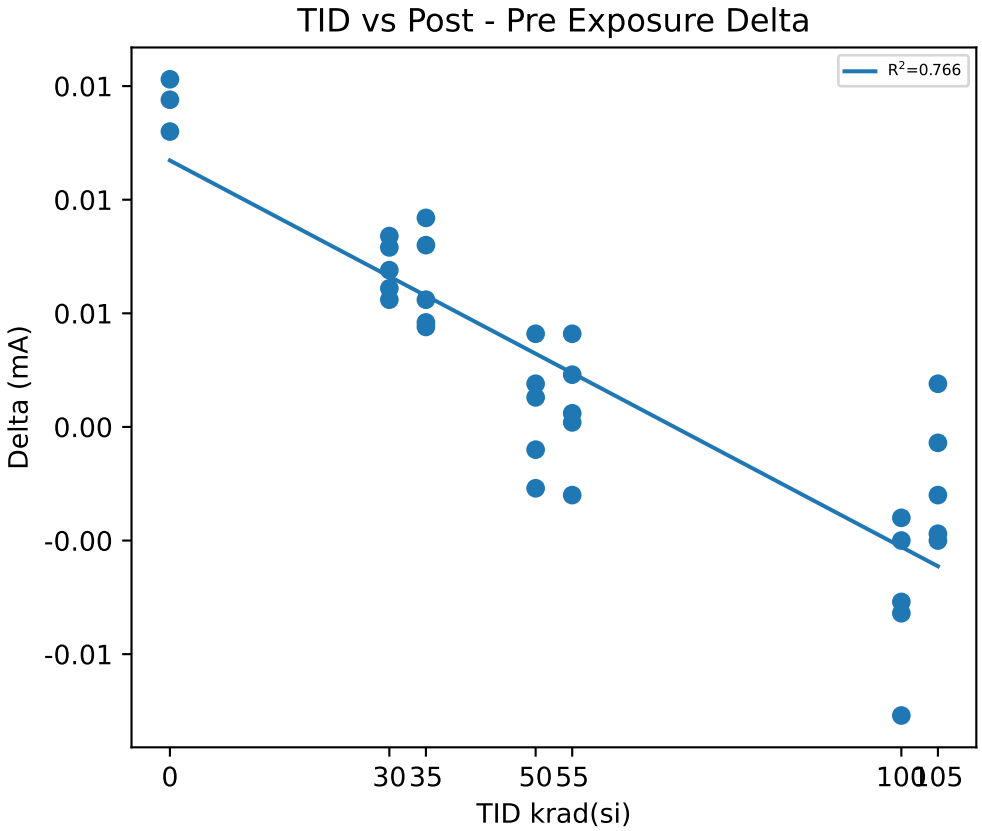
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6241	5.6852	5.7329	0.055612	5.6357	5.6955	5.7433	0.054795	0.009	0.010333	0.0116	0.0013013
30	5.695	5.7499	5.8434	0.062061	5.7213	5.7727	5.8735	0.063246	0.0146	0.02274	0.0311	0.0075408
35	5.5986	5.736	5.8101	0.080972	5.6122	5.7549	5.8257	0.083611	0.0136	0.01888	0.0292	0.0063935
50	5.5937	5.6573	5.7186	0.048913	5.6339	5.6908	5.7407	0.042488	0.0221	0.03344	0.0503	0.01159
55	5.5664	5.6769	5.8736	0.12201	5.599	5.7081	5.9059	0.12186	0.0242	0.0312	0.0361	0.0043686
100	5.506	5.6182	5.7894	0.105	5.5577	5.6646	5.8515	0.11135	0.0359	0.04632	0.0621	0.010555
105	5.5151	5.6196	5.7117	0.08166	5.5457	5.6455	5.7259	0.078228	0.0142	0.02584	0.0362	0.0089938

Device Test: 18.4 _IQ|ActiveHSoffLSon/PVIN/3/3/0/0/90.9/634//1.8//pre/@IQ_PVIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



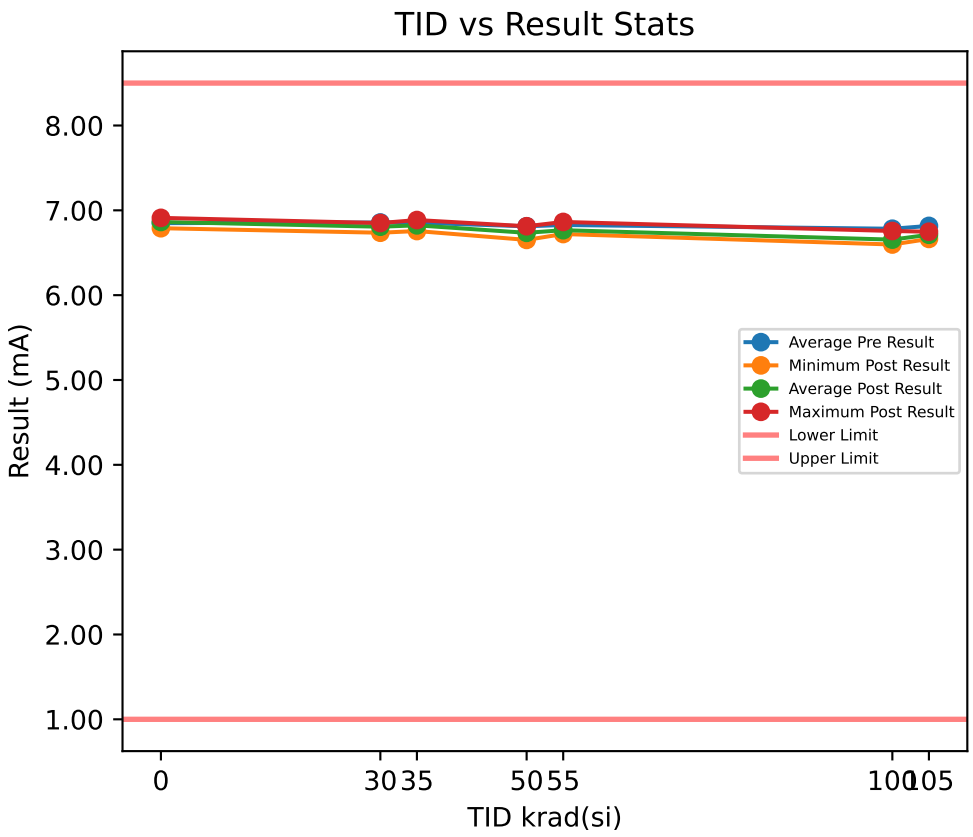
Test Results (Lower Limit = 1.0, Upper Limit = 3.7 (mA))

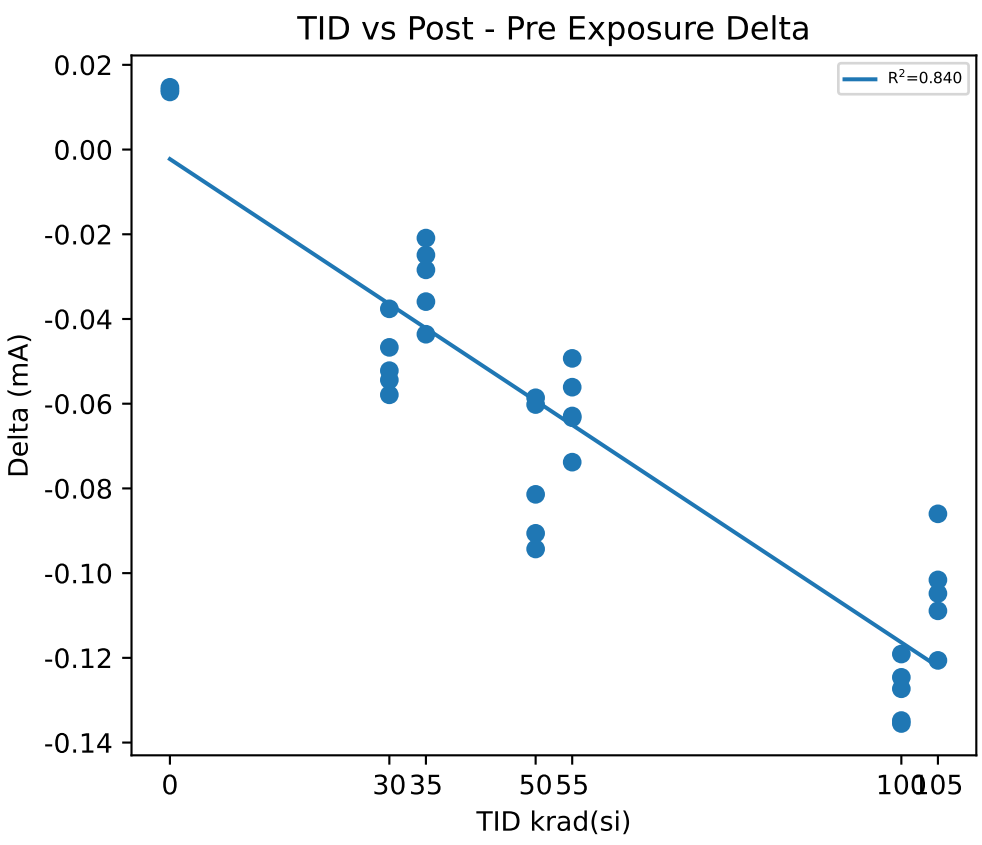
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.8123	1.8276	0.0153
2	0	CU2	1.8044	1.8188	0.0144
3	0	CU3	1.8	1.813	0.013
11	30	Unbiased-30krad	1.7834	1.7918	0.0084
12	30	Unbiased-30krad	1.8199	1.826	0.0061
13	30	Unbiased-30krad	1.7933	1.8002	0.0069
14	30	Unbiased-30krad	1.7635	1.7691	0.0056
15	30	Unbiased-30krad	1.8407	1.8486	0.0079
16	35	Biased-30krad	1.7954	1.8046	0.0092
17	35	Biased-30krad	1.8073	1.8129	0.0056
18	35	Biased-30krad	1.8335	1.8415	0.008
19	35	Biased-30krad	1.8374	1.8418	0.0044
20	35	Biased-30krad	1.8093	1.8139	0.0046
30	50	Unbiased-50krad	1.7965	1.7955	-0.001
31	50	Unbiased-50krad	1.7974	1.7947	-0.0027
32	50	Unbiased-50krad	1.7946	1.7965	0.0019
33	50	Unbiased-50krad	1.7977	1.799	0.0013
34	50	Unbiased-50krad	1.7855	1.7896	0.0041
40	55	Biased-50krad	1.8163	1.8133	-0.003
41	55	Biased-50krad	1.8463	1.8486	0.0023
42	55	Biased-50krad	1.8432	1.8473	0.0041
43	55	Biased-50krad	1.8224	1.823	0.0006
44	55	Biased-50krad	1.8154	1.8156	0.0002
45	100	Unbiased-100krad	1.8139	1.8057	-0.0082
46	100	Unbiased-100krad	1.7993	1.7916	-0.0077
47	100	Unbiased-100krad	1.813	1.8003	-0.0127
48	100	Unbiased-100krad	1.8082	1.8032	-0.005
49	100	Unbiased-100krad	1.8358	1.8318	-0.004
50	105	Biased-100krad	1.8163	1.8182	0.0019
51	105	Biased-100krad	1.8388	1.8338	-0.005
52	105	Biased-100krad	1.8052	1.8005	-0.0047
53	105	Biased-100krad	1.7816	1.7786	-0.003
54	105	Biased-100krad	1.7904	1.7897	-0.0007

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8	1.8056	1.8123	0.0062324	1.813	1.8198	1.8276	0.0073512	0.013	0.014233	0.0153	0.001159
30	1.7635	1.8002	1.8407	0.030435	1.7691	1.8071	1.8486	0.030843	0.0056	0.00698	0.0084	0.0011777
35	1.7954	1.8166	1.8374	0.018079	1.8046	1.8229	1.8418	0.017457	0.0044	0.00636	0.0092	0.0021373
50	1.7855	1.7943	1.7977	0.0050875	1.7896	1.7951	1.799	0.0034544	-0.0027	0.00072	0.0041	0.0026367
55	1.8154	1.8287	1.8463	0.014919	1.8133	1.8296	1.8486	0.017172	-0.003	0.00084	0.0041	0.0026444
100	1.7993	1.814	1.8358	0.013472	1.7916	1.8065	1.8318	0.0151	-0.0127	-0.00752	-0.004	0.0033937
105	1.7816	1.8065	1.8388	0.022473	1.7786	1.8042	1.8338	0.022088	-0.005	-0.0023	0.0019	0.0029043

Device Test: 19.1 _IQ|ShutDown/VIN/7/7/0/0/90.9/634//1.8//pre/@VIN_SHDN_CURR





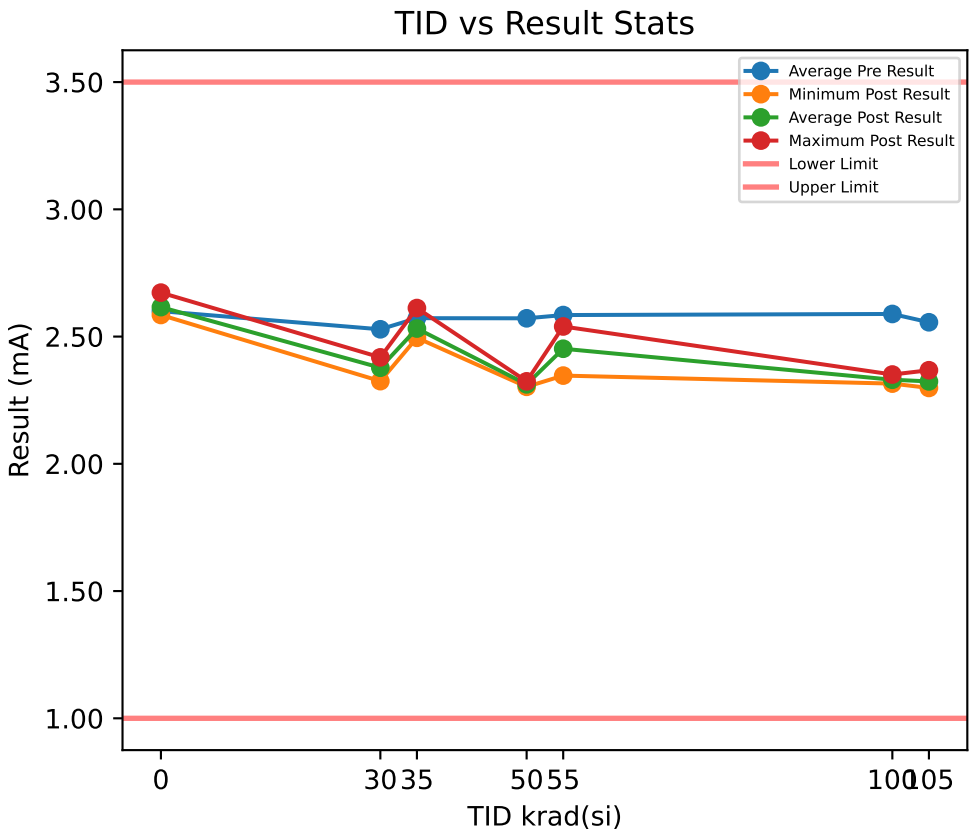
Test Results (Lower Limit = 1.0, Upper Limit = 8.5 (mA))

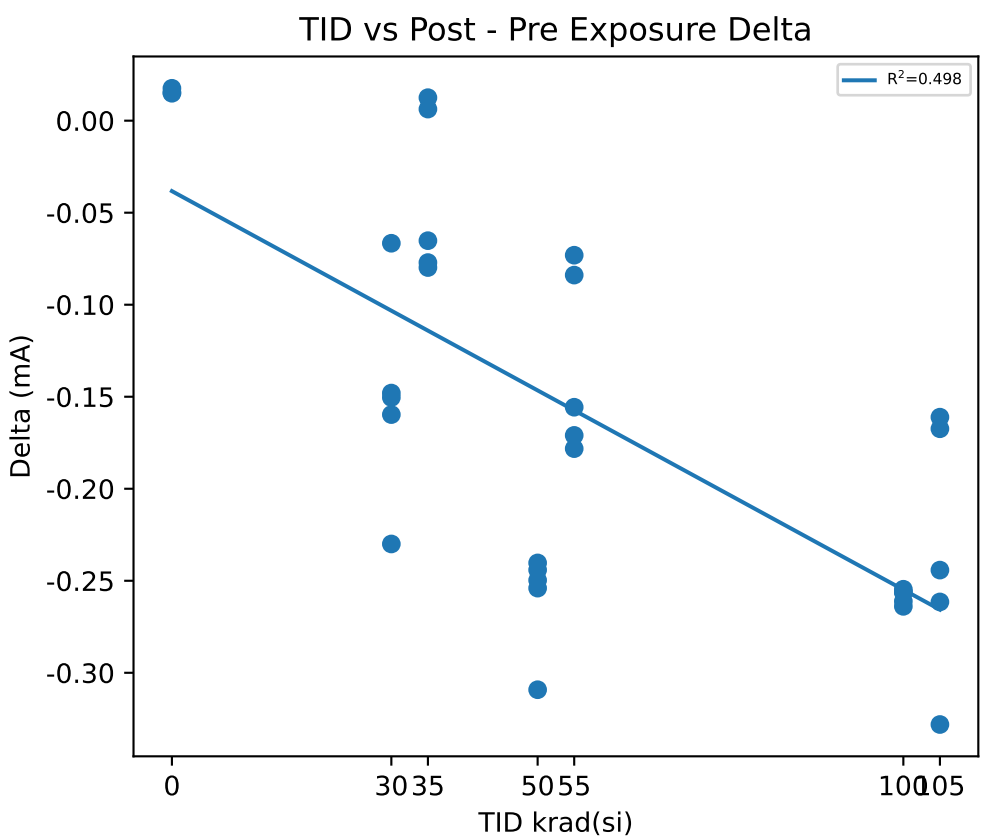
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.8971	6.9112	0.0141
2	0	CU2	6.7746	6.7893	0.0147
3	0	CU3	6.8744	6.888	0.0136
11	30	Unbiased-30krad	6.8701	6.8325	-0.0376
12	30	Unbiased-30krad	6.8465	6.7998	-0.0467
13	30	Unbiased-30krad	6.9081	6.8502	-0.0579
14	30	Unbiased-30krad	6.7904	6.736	-0.0544
15	30	Unbiased-30krad	6.8682	6.816	-0.0522
16	35	Biased-30krad	6.8615	6.8256	-0.0359
17	35	Biased-30krad	6.9065	6.8856	-0.0209
18	35	Biased-30krad	6.816	6.7911	-0.0249
19	35	Biased-30krad	6.8855	6.8571	-0.0284
20	35	Biased-30krad	6.7995	6.7559	-0.0436
30	50	Unbiased-50krad	6.7767	6.7165	-0.0602
31	50	Unbiased-50krad	6.7946	6.736	-0.0586
32	50	Unbiased-50krad	6.7328	6.6514	-0.0814
33	50	Unbiased-50krad	6.9067	6.8124	-0.0943
34	50	Unbiased-50krad	6.8486	6.758	-0.0906
40	55	Biased-50krad	6.7821	6.7328	-0.0493
41	55	Biased-50krad	6.8269	6.7531	-0.0738
42	55	Biased-50krad	6.926	6.8631	-0.0629
43	55	Biased-50krad	6.8233	6.76	-0.0633
44	55	Biased-50krad	6.7768	6.7207	-0.0561
45	100	Unbiased-100krad	6.7899	6.6653	-0.1246
46	100	Unbiased-100krad	6.7326	6.5971	-0.1355
47	100	Unbiased-100krad	6.7846	6.6498	-0.1348
48	100	Unbiased-100krad	6.8756	6.7565	-0.1191
49	100	Unbiased-100krad	6.7323	6.605	-0.1273
50	105	Biased-100krad	6.8151	6.7135	-0.1016
51	105	Biased-100krad	6.7941	6.7081	-0.086
52	105	Biased-100krad	6.7719	6.663	-0.1089
53	105	Biased-100krad	6.848	6.7274	-0.1206
54	105	Biased-100krad	6.8526	6.7478	-0.1048

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7746	6.8487	6.8971	0.065168	6.7893	6.8628	6.9112	0.06473	0.0136	0.014133	0.0147	0.00055076
30	6.7904	6.8567	6.9081	0.043167	6.736	6.8069	6.8502	0.043847	-0.0579	-0.04976	-0.0376	0.007921
35	6.7995	6.8538	6.9065	0.045329	6.7559	6.8231	6.8856	0.051498	-0.0436	-0.03074	-0.0209	0.0090611
50	6.7328	6.8119	6.9067	0.067322	6.6514	6.7349	6.8124	0.058847	-0.0943	-0.07702	-0.0586	0.016766
55	6.7768	6.827	6.926	0.059897	6.7207	6.7659	6.8631	0.056536	-0.0738	-0.06108	-0.0493	0.0091325
100	6.7323	6.783	6.8756	0.058599	6.5971	6.6547	6.7565	0.063811	-0.1355	-0.12826	-0.1191	0.0069536
105	6.7719	6.8163	6.8526	0.034598	6.663	6.712	6.7478	0.031374	-0.1206	-0.10438	-0.086	0.012542

Device Test: 19.2 _IQ|ShutDown/PVIN/7/7/0/0/90.9/634//1.8//pre/@PVIN_SHDN_CURR





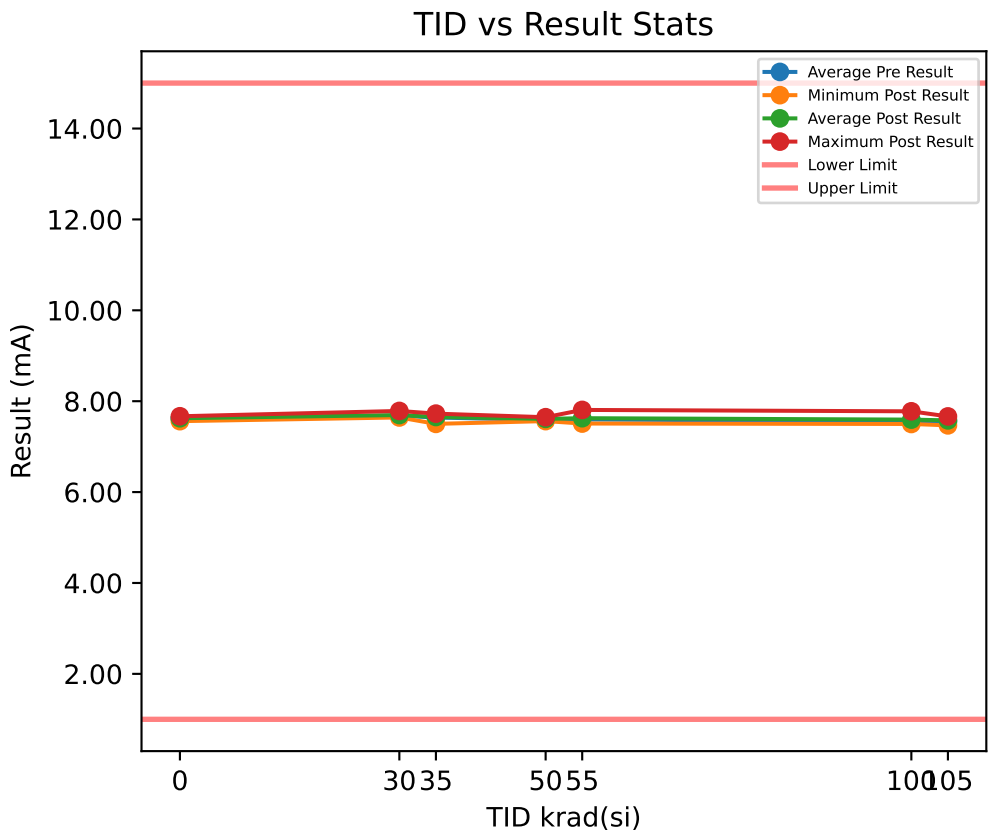
Test Results (Lower Limit = 1.0, Upper Limit = 3.5 (mA))

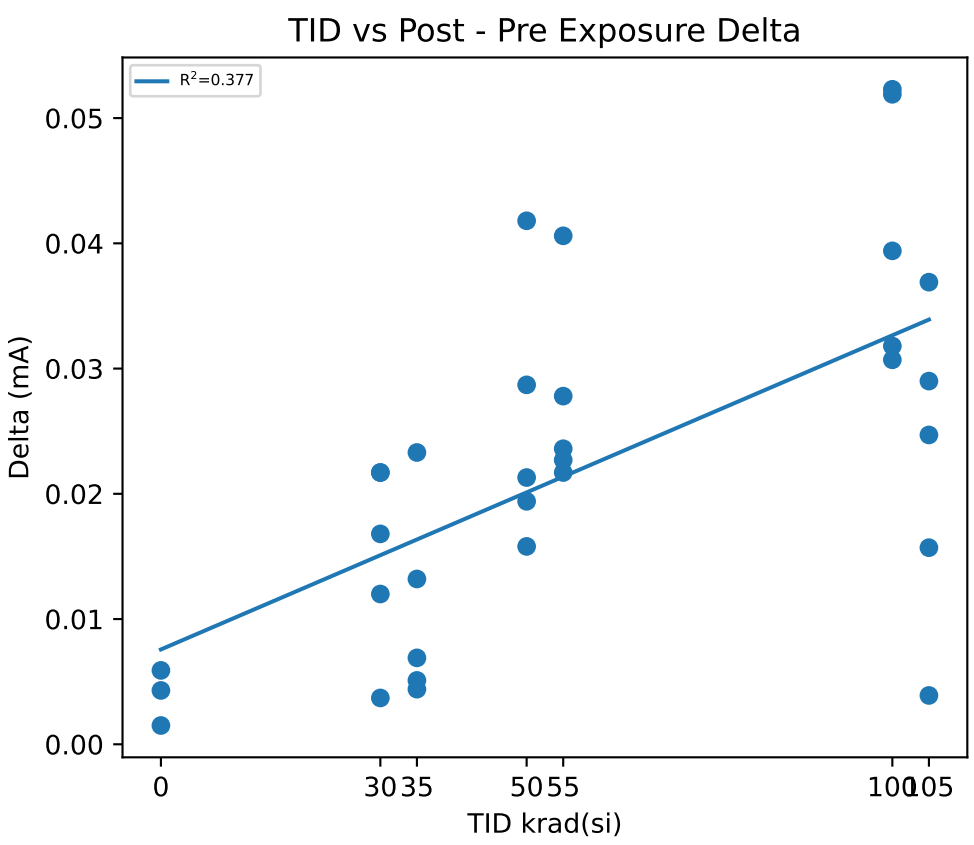
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5722	2.5898	0.0176
2	0	CU2	2.5696	2.5849	0.0153
3	0	CU3	2.6578	2.6727	0.0149
11	30	Unbiased-30krad	2.4696	2.403	-0.0666
12	30	Unbiased-30krad	2.5663	2.4183	-0.148
13	30	Unbiased-30krad	2.4846	2.3249	-0.1597
14	30	Unbiased-30krad	2.5224	2.372	-0.1504
15	30	Unbiased-30krad	2.6001	2.3701	-0.23
16	35	Biased-30krad	2.5604	2.4952	-0.0652
17	35	Biased-30krad	2.5842	2.5071	-0.0771
18	35	Biased-30krad	2.5996	2.6121	0.0125
19	35	Biased-30krad	2.5302	2.5365	0.0063
20	35	Biased-30krad	2.5872	2.5074	-0.0798
30	50	Unbiased-50krad	2.5612	2.3072	-0.254
31	50	Unbiased-50krad	2.5668	2.3171	-0.2497
32	50	Unbiased-50krad	2.5509	2.3106	-0.2403
33	50	Unbiased-50krad	2.5682	2.3241	-0.2441
34	50	Unbiased-50krad	2.6118	2.3026	-0.3092
40	55	Biased-50krad	2.6059	2.4277	-0.1782
41	55	Biased-50krad	2.6128	2.5397	-0.0731
42	55	Biased-50krad	2.5958	2.4401	-0.1557
43	55	Biased-50krad	2.5907	2.5068	-0.0839
44	55	Biased-50krad	2.5177	2.3467	-0.171
45	100	Unbiased-100krad	2.6001	2.3362	-0.2639
46	100	Unbiased-100krad	2.5717	2.3152	-0.2565
47	100	Unbiased-100krad	2.5868	2.3257	-0.2611
48	100	Unbiased-100krad	2.5788	2.3242	-0.2546
49	100	Unbiased-100krad	2.6068	2.3509	-0.2559
50	105	Biased-100krad	2.5003	2.3329	-0.1674
51	105	Biased-100krad	2.5288	2.3677	-0.1611
52	105	Biased-100krad	2.5592	2.315	-0.2442
53	105	Biased-100krad	2.5597	2.2982	-0.2615
54	105	Biased-100krad	2.6332	2.3051	-0.3281

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5696	2.5999	2.6578	0.050189	2.5849	2.6158	2.6727	0.049338	0.0149	0.015933	0.0176	0.0014572
30	2.4696	2.5286	2.6001	0.054747	2.3249	2.3777	2.4183	0.035939	-0.23	-0.15094	-0.0666	0.057986
35	2.5302	2.5723	2.5996	0.027491	2.4952	2.5317	2.6121	0.047474	-0.0798	-0.04066	0.0125	0.046079
50	2.5509	2.5718	2.6118	0.023383	2.3026	2.3123	2.3241	0.0084449	-0.3092	-0.25946	-0.2403	0.028294
55	2.5177	2.5846	2.6128	0.038364	2.3467	2.4522	2.5397	0.075024	-0.1782	-0.13238	-0.0731	0.049998
100	2.5717	2.5888	2.6068	0.014561	2.3152	2.3304	2.3509	0.013651	-0.2639	-0.2584	-0.2546	0.0039319
105	2.5003	2.5562	2.6332	0.049563	2.2982	2.3238	2.3677	0.027805	-0.3281	-0.23246	-0.1611	0.069737

Device Test: 19.3 _IQ|ActiveHSoffLSon/VIN/7/7/0/0/90.9/634//1.8//pre/@IQ_VIN





Test Results (Lower Limit = 1.0, Upper Limit = 15.0 (mA))

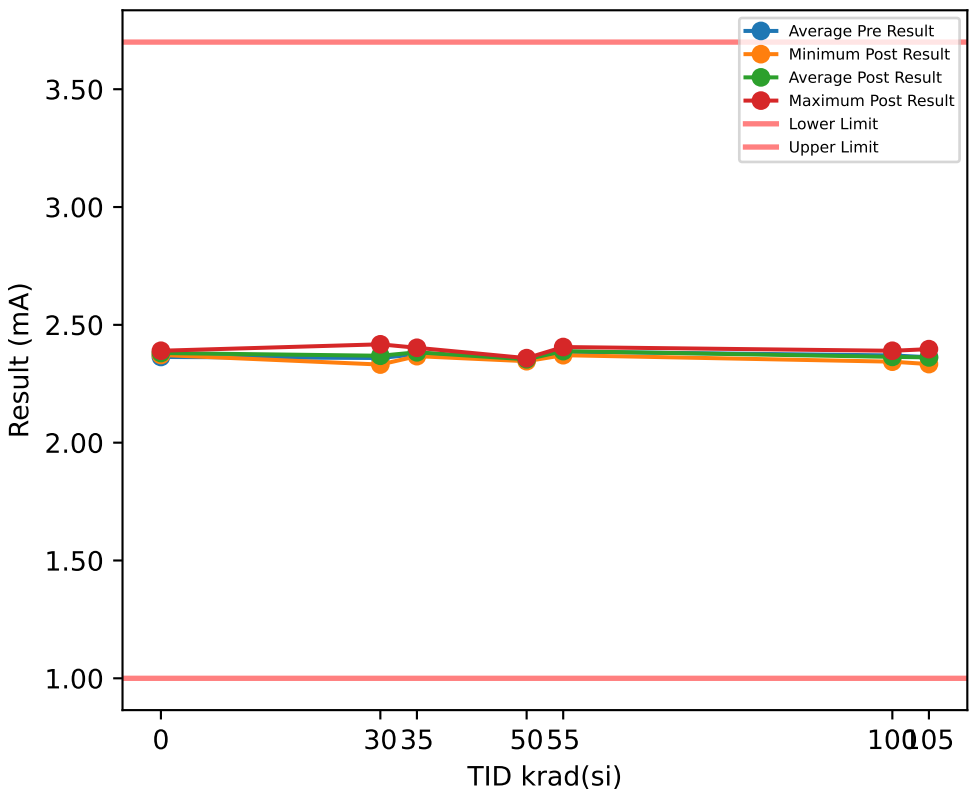
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	7.6667	7.6682	0.0015
2	0	CU2	7.555	7.5609	0.0059
3	0	CU3	7.641	7.6453	0.0043
11	30	Unbiased-30krad	7.6629	7.6797	0.0168
12	30	Unbiased-30krad	7.709	7.7127	0.0037
13	30	Unbiased-30krad	7.7637	7.7854	0.0217
14	30	Unbiased-30krad	7.6204	7.6421	0.0217
15	30	Unbiased-30krad	7.6442	7.6562	0.012
16	35	Biased-30krad	7.6538	7.6607	0.0069
17	35	Biased-30krad	7.6751	7.6984	0.0233
18	35	Biased-30krad	7.6615	7.6747	0.0132
19	35	Biased-30krad	7.7219	7.7263	0.0044
20	35	Biased-30krad	7.496	7.5011	0.0051
30	50	Unbiased-50krad	7.5827	7.6245	0.0418
31	50	Unbiased-50krad	7.5542	7.5755	0.0213
32	50	Unbiased-50krad	7.5332	7.5619	0.0287
33	50	Unbiased-50krad	7.6301	7.6459	0.0158
34	50	Unbiased-50krad	7.6282	7.6476	0.0194
40	55	Biased-50krad	7.5947	7.6353	0.0406
41	55	Biased-50krad	7.6227	7.6463	0.0236
42	55	Biased-50krad	7.7862	7.8079	0.0217
43	55	Biased-50krad	7.5111	7.5338	0.0227
44	55	Biased-50krad	7.4804	7.5082	0.0278
45	100	Unbiased-100krad	7.5453	7.576	0.0307
46	100	Unbiased-100krad	7.4469	7.4988	0.0519
47	100	Unbiased-100krad	7.5186	7.558	0.0394
48	100	Unbiased-100krad	7.7251	7.7774	0.0523
49	100	Unbiased-100krad	7.5342	7.566	0.0318
50	105	Biased-100krad	7.6338	7.6377	0.0039
51	105	Biased-100krad	7.444	7.4687	0.0247
52	105	Biased-100krad	7.5281	7.5438	0.0157
53	105	Biased-100krad	7.5394	7.5763	0.0369
54	105	Biased-100krad	7.6358	7.6648	0.029

Test Statistics (mA)

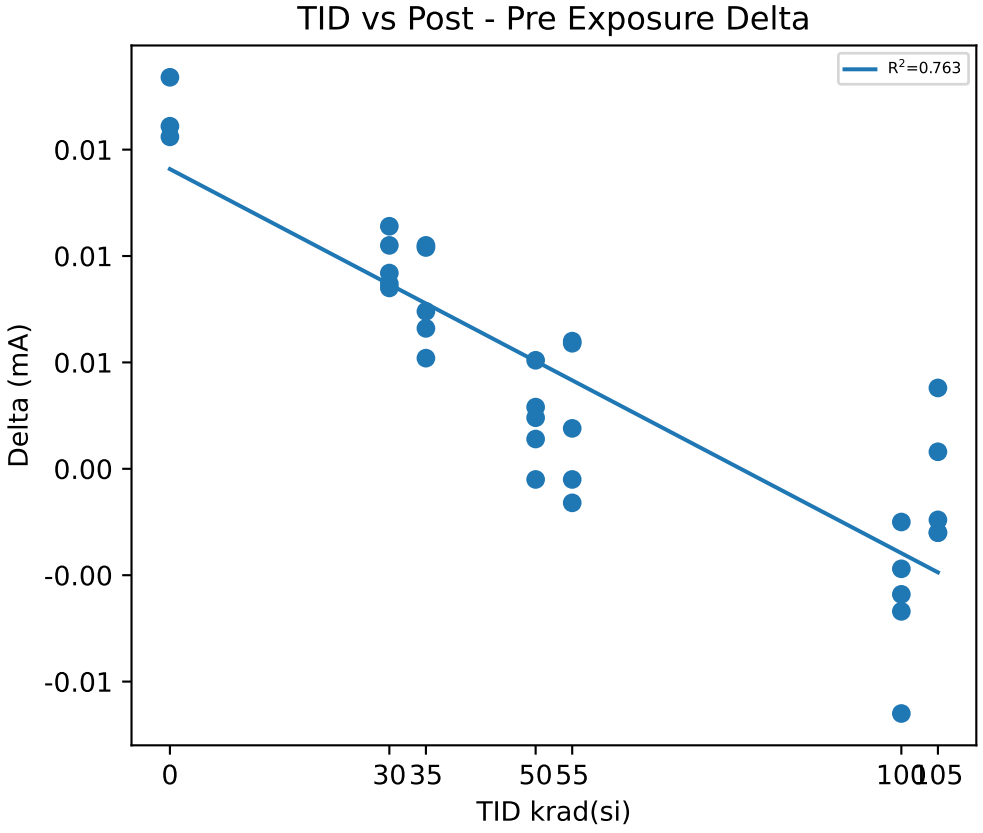
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.555	7.6209	7.6667	0.0585	7.5609	7.6248	7.6682	0.056511	0.0015	0.0039	0.0059	0.0022271
30	7.6204	7.68	7.7637	0.056949	7.6421	7.6952	7.7854	0.05706	0.0037	0.01518	0.0217	0.0075754
35	7.496	7.6417	7.7219	0.085607	7.5011	7.6522	7.7263	0.088084	0.0044	0.01058	0.0233	0.0079125
50	7.5332	7.5857	7.6301	0.043402	7.5619	7.6111	7.6476	0.040034	0.0158	0.0254	0.0418	0.010306
55	7.4804	7.599	7.7862	0.11981	7.5082	7.6263	7.8079	0.11828	0.0217	0.02728	0.0406	0.0077998
100	7.4469	7.554	7.7251	0.10304	7.4988	7.5952	7.7774	0.10618	0.0307	0.04122	0.0523	0.010483
105	7.444	7.5562	7.6358	0.080651	7.4687	7.5783	7.6648	0.077809	0.0039	0.02204	0.0369	0.012704

Device Test: 19.4 _IQ|ActiveHSoffLSon/PVIN/7/7/0/0/90.9/634//1.8//pre/@IQ_PVIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



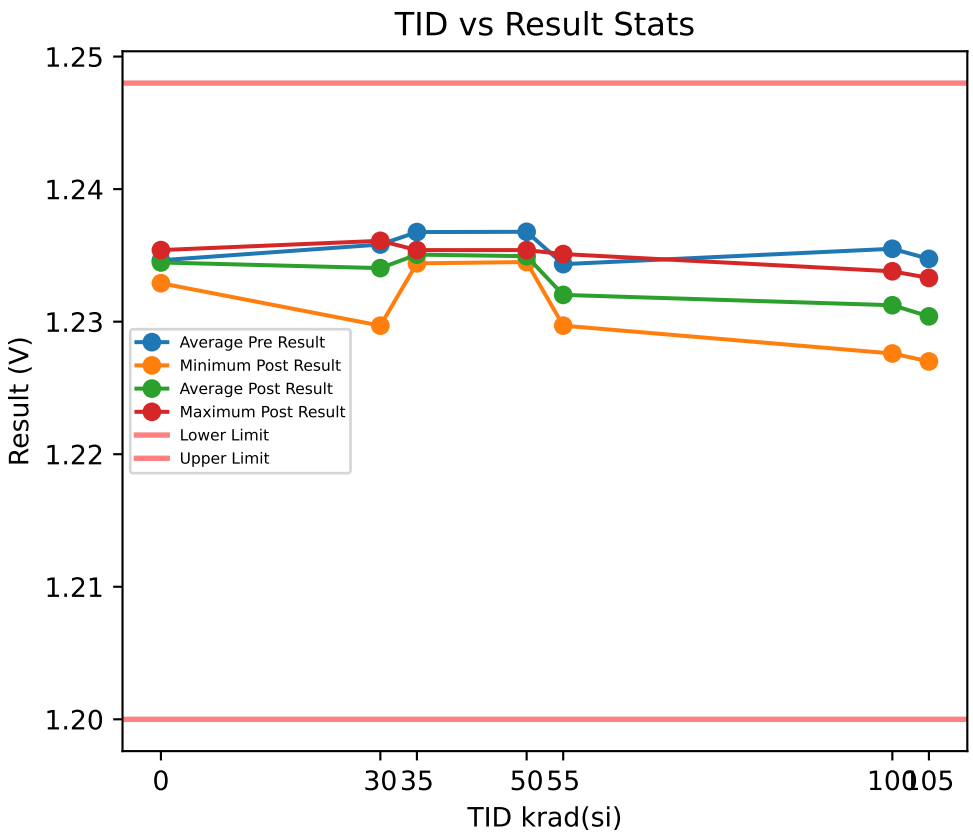
Test Results (Lower Limit = 1.0, Upper Limit = 3.7 (mA))

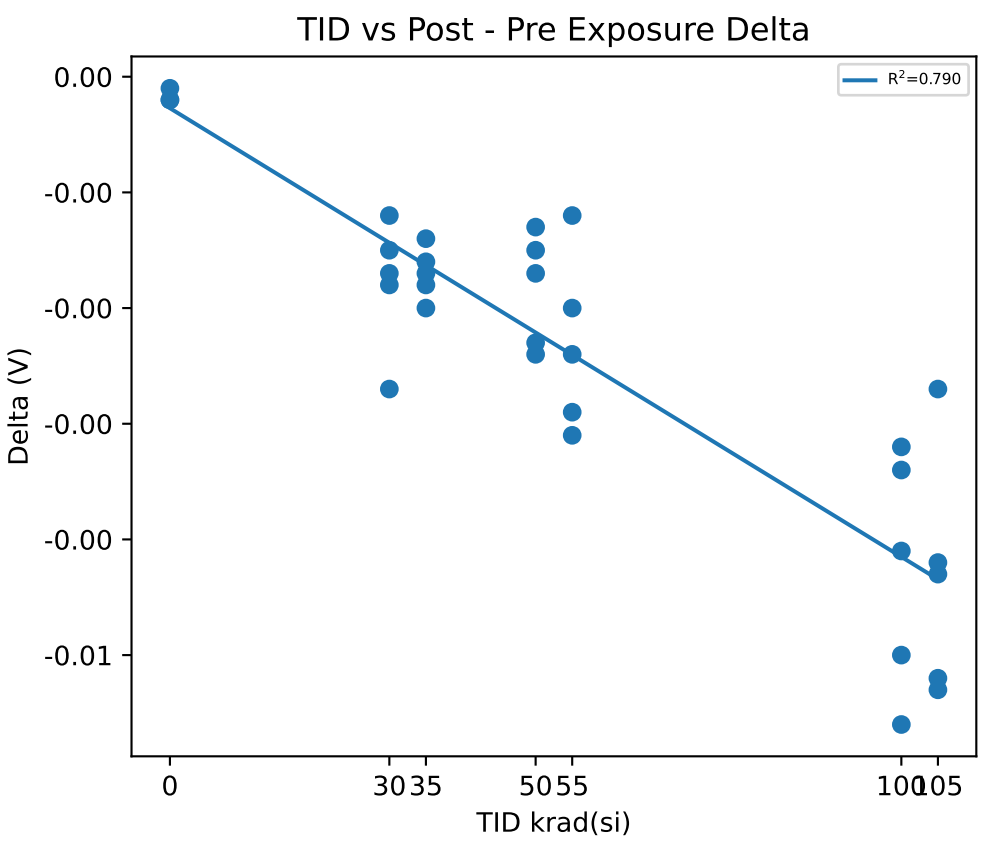
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3717	2.3901	0.0184
2	0	CU2	2.3561	2.3722	0.0161
3	0	CU3	2.3634	2.379	0.0156
11	30	Unbiased-30krad	2.3445	2.355	0.0105
12	30	Unbiased-30krad	2.3712	2.3799	0.0087
13	30	Unbiased-30krad	2.3514	2.3606	0.0092
14	30	Unbiased-30krad	2.323	2.3315	0.0085
15	30	Unbiased-30krad	2.406	2.4174	0.0114
16	35	Biased-30krad	2.3566	2.3671	0.0105
17	35	Biased-30krad	2.3693	2.3767	0.0074
18	35	Biased-30krad	2.3863	2.3967	0.0104
19	35	Biased-30krad	2.3961	2.4027	0.0066
20	35	Biased-30krad	2.3692	2.3744	0.0052
30	50	Unbiased-50krad	2.351	2.3524	0.0014
31	50	Unbiased-50krad	2.3559	2.3554	-0.0005
32	50	Unbiased-50krad	2.3558	2.3587	0.0029
33	50	Unbiased-50krad	2.3547	2.3571	0.0024
34	50	Unbiased-50krad	2.3406	2.3457	0.0051
40	55	Biased-50krad	2.3728	2.3712	-0.0016
41	55	Biased-50krad	2.3999	2.4059	0.006
42	55	Biased-50krad	2.3985	2.4044	0.0059
43	55	Biased-50krad	2.3835	2.3854	0.0019
44	55	Biased-50krad	2.3763	2.3758	-0.0005
45	100	Unbiased-100krad	2.3762	2.3695	-0.0067
46	100	Unbiased-100krad	2.3496	2.3437	-0.0059
47	100	Unbiased-100krad	2.369	2.3575	-0.0115
48	100	Unbiased-100krad	2.3642	2.3595	-0.0047
49	100	Unbiased-100krad	2.3925	2.39	-0.0025
50	105	Biased-100krad	2.3759	2.3797	0.0038
51	105	Biased-100krad	2.3999	2.3969	-0.003
52	105	Biased-100krad	2.3563	2.3533	-0.003
53	105	Biased-100krad	2.3359	2.3335	-0.0024
54	105	Biased-100krad	2.3453	2.3461	0.0008

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3561	2.3637	2.3717	0.0078053	2.3722	2.3804	2.3901	0.0090357	0.0156	0.0167	0.0184	0.0014933
30	2.323	2.3592	2.406	0.031311	2.3315	2.3689	2.4174	0.032149	0.0085	0.00966	0.0114	0.0012462
35	2.3566	2.3755	2.3961	0.015623	2.3671	2.3835	2.4027	0.015337	0.0052	0.00802	0.0105	0.0023541
50	2.3406	2.3516	2.3559	0.0064634	2.3457	2.3539	2.3587	0.0051238	-0.0005	0.00226	0.0051	0.0020526
55	2.3728	2.3862	2.3999	0.012488	2.3712	2.3885	2.4059	0.016014	-0.0016	0.00234	0.006	0.0035303
100	2.3496	2.3703	2.3925	0.015772	2.3437	2.364	2.39	0.017182	-0.0115	-0.00626	-0.0025	0.0033299
105	2.3359	2.3627	2.3999	0.025593	2.3335	2.3619	2.3969	0.025846	-0.003	-0.00076	0.0038	0.002998

Device Test: 21.1 _REF|REFCAP/REFCAP/3/3/0/0/90.9/634//1.8//25C/@VREFCAP





Test Results (Lower Limit = 1.2, Upper Limit = 1.248 (V))

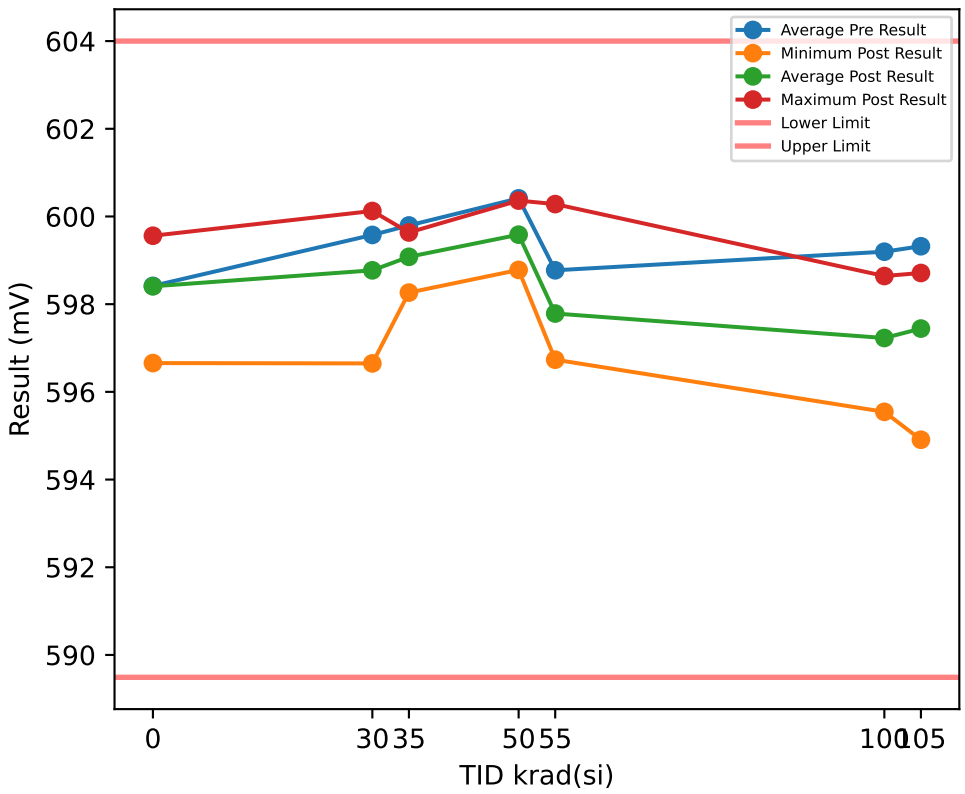
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.2353	1.2351	-0.0002
2	0	CU2	1.2331	1.2329	-0.0002
3	0	CU3	1.2355	1.2354	-0.0001
11	30	Unbiased-30krad	1.2315	1.2297	-0.0018
12	30	Unbiased-30krad	1.2376	1.2361	-0.0015
13	30	Unbiased-30krad	1.237	1.2353	-0.0017
14	30	Unbiased-30krad	1.2366	1.2339	-0.0027
15	30	Unbiased-30krad	1.2364	1.2352	-0.0012
16	35	Biased-30krad	1.2365	1.2351	-0.0014
17	35	Biased-30krad	1.236	1.2344	-0.0016
18	35	Biased-30krad	1.237	1.2352	-0.0018
19	35	Biased-30krad	1.2374	1.2354	-0.002
20	35	Biased-30krad	1.2369	1.2352	-0.0017
30	50	Unbiased-50krad	1.2364	1.2351	-0.0013
31	50	Unbiased-50krad	1.2368	1.2345	-0.0023
32	50	Unbiased-50krad	1.2378	1.2354	-0.0024
33	50	Unbiased-50krad	1.2368	1.2351	-0.0017
34	50	Unbiased-50krad	1.2361	1.2346	-0.0015
40	55	Biased-50krad	1.2339	1.2308	-0.0031
41	55	Biased-50krad	1.2359	1.233	-0.0029
42	55	Biased-50krad	1.2321	1.2297	-0.0024
43	55	Biased-50krad	1.2335	1.2315	-0.002
44	55	Biased-50krad	1.2363	1.2351	-0.0012
45	100	Unbiased-100krad	1.2361	1.2311	-0.005
46	100	Unbiased-100krad	1.237	1.2338	-0.0032
47	100	Unbiased-100krad	1.2371	1.2315	-0.0056
48	100	Unbiased-100krad	1.231	1.2276	-0.0034
49	100	Unbiased-100krad	1.2363	1.2322	-0.0041
50	105	Biased-100krad	1.236	1.2333	-0.0027
51	105	Biased-100krad	1.2371	1.2318	-0.0053
52	105	Biased-100krad	1.2339	1.2297	-0.0042
53	105	Biased-100krad	1.2322	1.227	-0.0052
54	105	Biased-100krad	1.2345	1.2302	-0.0043

Test Statistics (V)

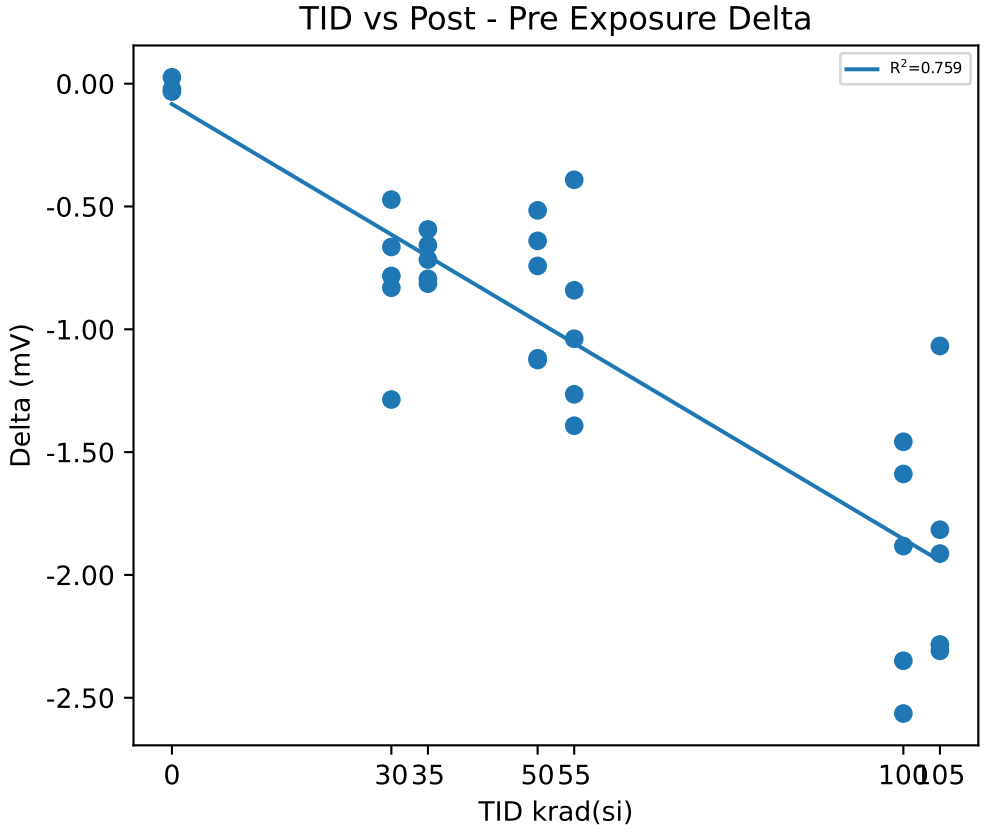
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2331	1.2346	1.2355	0.0013317	1.2329	1.2345	1.2354	0.001365	-0.0002	-0.00016667	-0.0001	5.7735e-05
30	1.2315	1.2358	1.2376	0.002458	1.2297	1.234	1.2361	0.0025511	-0.0027	-0.00178	-0.0012	0.00056303
35	1.236	1.2368	1.2374	0.00053198	1.2344	1.2351	1.2354	0.00038471	-0.002	-0.0017	-0.0014	0.00022361
50	1.2361	1.2368	1.2378	0.00064187	1.2345	1.2349	1.2354	0.00037815	-0.0024	-0.00184	-0.0013	0.00048785
55	1.2321	1.2343	1.2363	0.0017459	1.2297	1.232	1.2351	0.0020969	-0.0031	-0.00232	-0.0012	0.00075961
100	1.231	1.2355	1.2371	0.0025524	1.2276	1.2312	1.2338	0.002281	-0.0056	-0.00426	-0.0032	0.0010286
105	1.2322	1.2347	1.2371	0.0018955	1.227	1.2304	1.2333	0.0023696	-0.0053	-0.00434	-0.0027	0.0010455

Device Test: 21.2 _REF|VREF/VREF1/3/3/0/0/90.9/634//1.8//25C/@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



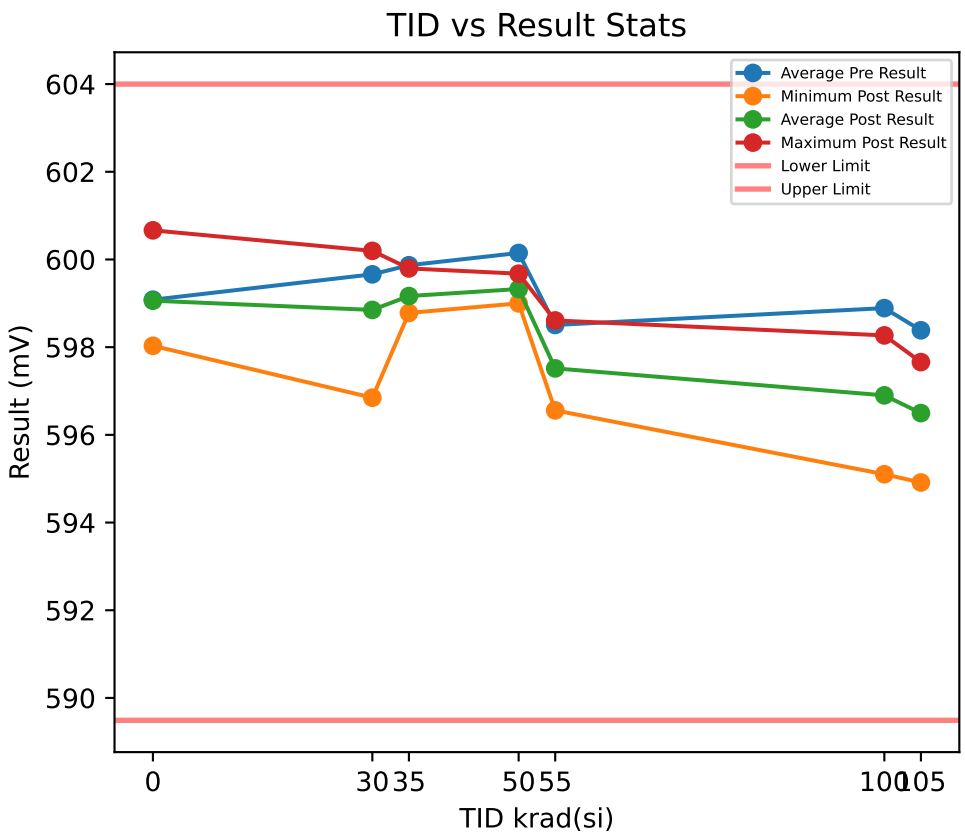
Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

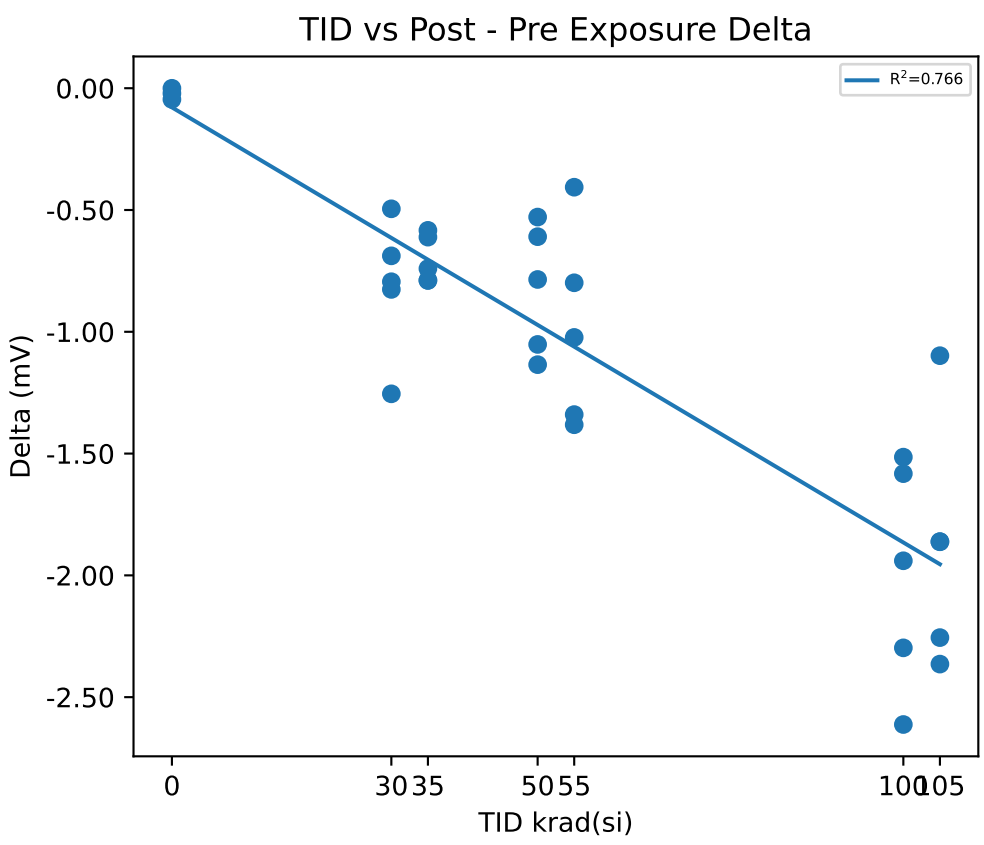
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.58	599.56	-0.022
2	0	CU2	596.69	596.66	-0.0322
3	0	CU3	598.98	599.01	0.0259
11	30	Unbiased-30krad	597.72	596.89	-0.8307
12	30	Unbiased-30krad	600.79	600.12	-0.6648
13	30	Unbiased-30krad	600.88	600.1	-0.7829
14	30	Unbiased-30krad	597.93	596.65	-1.2859
15	30	Unbiased-30krad	600.57	600.1	-0.4721
16	35	Biased-30krad	599.83	599.24	-0.5933
17	35	Biased-30krad	599.98	599.33	-0.6574
18	35	Biased-30krad	599.06	598.26	-0.7946
19	35	Biased-30krad	600.45	599.64	-0.8142
20	35	Biased-30krad	599.65	598.94	-0.7162
30	50	Unbiased-50krad	600.88	600.36	-0.5159
31	50	Unbiased-50krad	600.45	599.33	-1.1181
32	50	Unbiased-50krad	601.03	599.91	-1.1252
33	50	Unbiased-50krad	600.29	599.54	-0.742
34	50	Unbiased-50krad	599.42	598.78	-0.64
40	55	Biased-50krad	598.55	597.16	-1.3925
41	55	Biased-50krad	598.91	597.65	-1.2647
42	55	Biased-50krad	597.77	596.73	-1.0385
43	55	Biased-50krad	597.95	597.11	-0.8411
44	55	Biased-50krad	600.67	600.28	-0.3914
45	100	Unbiased-100krad	599.19	596.84	-2.3492
46	100	Unbiased-100krad	600.1	598.64	-1.4579
47	100	Unbiased-100krad	599.87	597.3	-2.5641
48	100	Unbiased-100krad	597.13	595.54	-1.5889
49	100	Unbiased-100krad	599.7	597.81	-1.8826
50	105	Biased-100krad	599.78	598.71	-1.0678
51	105	Biased-100krad	600.51	598.2	-2.3091
52	105	Biased-100krad	599.6	597.69	-1.9129
53	105	Biased-100krad	597.19	594.91	-2.283
54	105	Biased-100krad	599.52	597.71	-1.8159

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.69	598.42	599.58	1.5268	596.66	598.41	599.56	1.5416	-0.0322	-0.0094333	0.0259	0.031022
30	597.72	599.58	600.88	1.6051	596.65	598.77	600.12	1.8305	-1.2859	-0.80728	-0.4721	0.30119
35	599.06	599.8	600.45	0.50701	598.26	599.08	599.64	0.51988	-0.8142	-0.71514	-0.5933	0.09261
50	599.42	600.41	601.03	0.6331	598.78	599.58	600.36	0.5964	-1.1252	-0.82824	-0.5159	0.27957
55	597.77	598.77	600.67	1.1577	596.73	597.79	600.28	1.4326	-1.3925	-0.98564	-0.3914	0.39377
100	597.13	599.2	600.1	1.2012	595.54	597.23	598.64	1.1549	-2.5641	-1.9685	-1.4579	0.47746
105	597.19	599.32	600.51	1.253	594.91	597.44	598.71	1.4781	-2.3091	-1.8777	-1.0678	0.50283

Device Test: 21.3 _REF|VREF/VREF2/3/3/0/0/90.9/634//1.8//25C/@VREF_25C





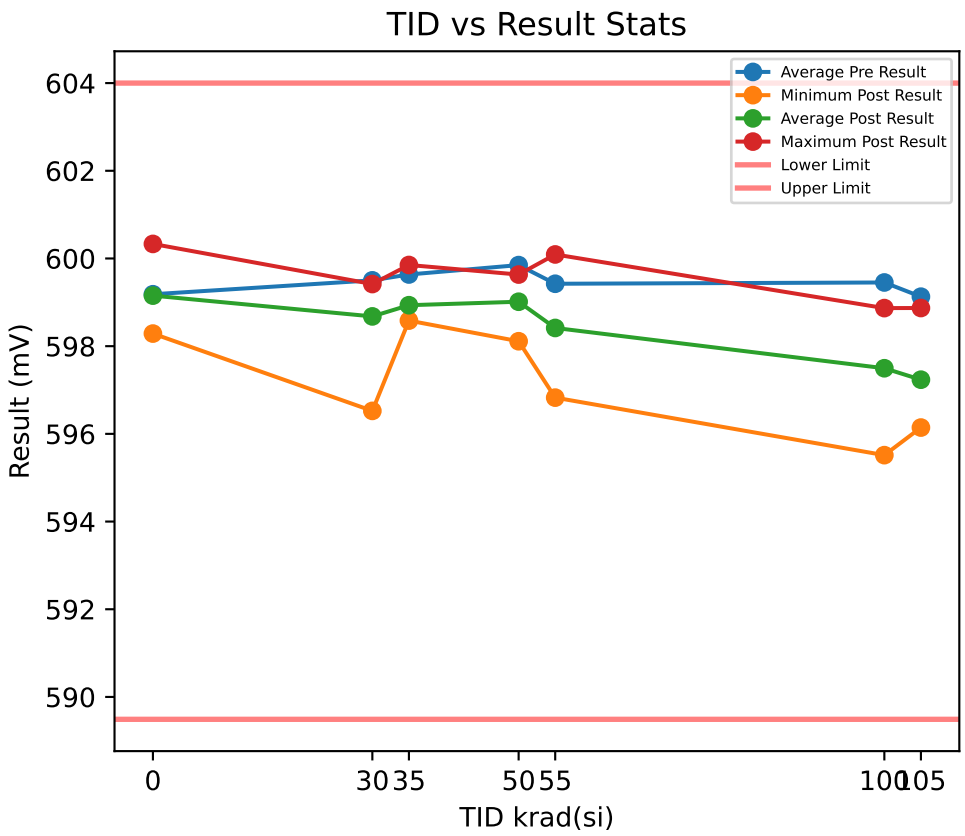
Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

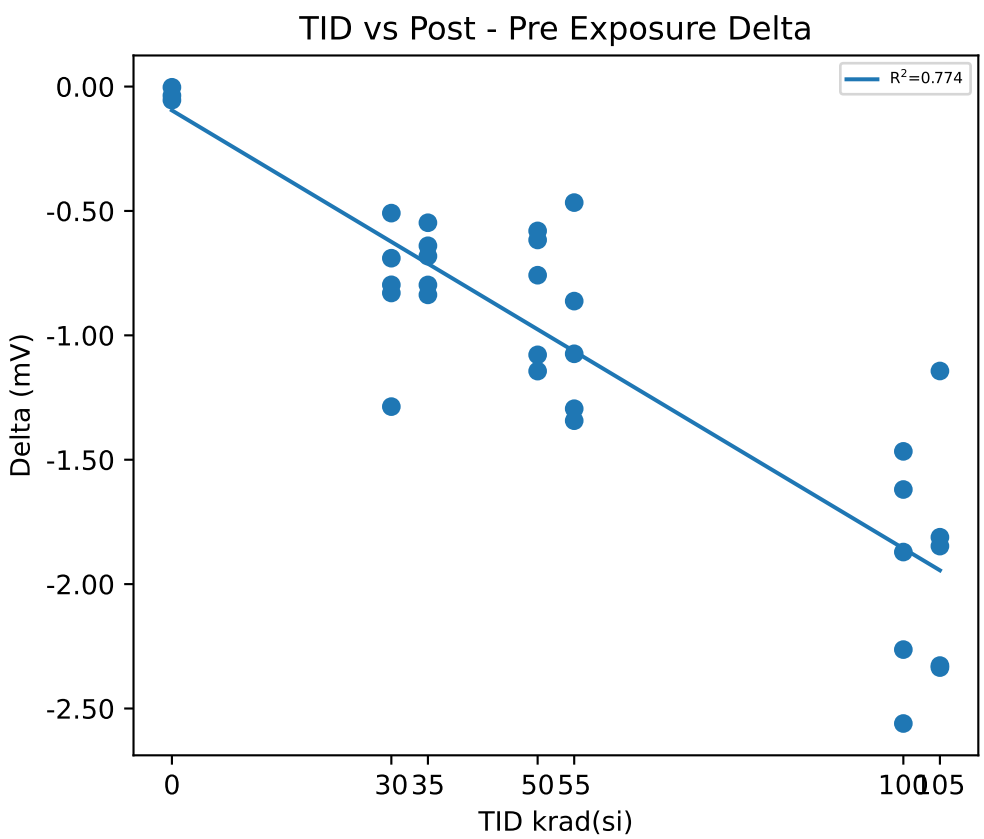
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.05	598.03	-0.0212
2	0	CU2	598.53	598.48	-0.0459
3	0	CU3	600.66	600.66	-0.0003
11	30	Unbiased-30krad	597.67	596.85	-0.826
12	30	Unbiased-30krad	600.88	600.2	-0.6882
13	30	Unbiased-30krad	599.55	598.76	-0.7945
14	30	Unbiased-30krad	599.89	598.64	-1.2547
15	30	Unbiased-30krad	600.3	599.81	-0.4951
16	35	Biased-30krad	599.36	598.78	-0.5835
17	35	Biased-30krad	599.75	599.14	-0.6114
18	35	Biased-30krad	600.58	599.8	-0.7884
19	35	Biased-30krad	599.63	598.84	-0.7892
20	35	Biased-30krad	600.01	599.27	-0.7406
30	50	Unbiased-50krad	600.21	599.68	-0.529
31	50	Unbiased-50krad	600.18	599.12	-1.0519
32	50	Unbiased-50krad	600.57	599.43	-1.1349
33	50	Unbiased-50krad	600.18	599.4	-0.7852
34	50	Unbiased-50krad	599.61	599	-0.6095
40	55	Biased-50krad	597.94	596.56	-1.3816
41	55	Biased-50krad	599.82	598.48	-1.3399
42	55	Biased-50krad	597.74	596.71	-1.0231
43	55	Biased-50krad	598.02	597.22	-0.7988
44	55	Biased-50krad	599.02	598.61	-0.4064
45	100	Unbiased-100krad	599.39	597.09	-2.2976
46	100	Unbiased-100krad	599.78	598.27	-1.5146
47	100	Unbiased-100krad	599.5	596.89	-2.6123
48	100	Unbiased-100krad	596.68	595.1	-1.5824
49	100	Unbiased-100krad	599.1	597.16	-1.9401
50	105	Biased-100krad	598.76	597.66	-1.0981
51	105	Biased-100krad	599.52	597.15	-2.3643
52	105	Biased-100krad	598.1	596.24	-1.8614
53	105	Biased-100krad	597.17	594.91	-2.2555
54	105	Biased-100krad	598.38	596.51	-1.8621

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.05	599.08	600.66	1.3911	598.03	599.06	600.66	1.408	-0.0459	-0.022467	-0.0003	0.022826
30	597.67	599.66	600.88	1.217	596.85	598.85	600.2	1.3032	-1.2547	-0.8117	-0.4951	0.27939
35	599.36	599.87	600.58	0.46224	598.78	599.17	599.8	0.40607	-0.7892	-0.70262	-0.5835	0.098498
50	599.61	600.15	600.57	0.34377	599	599.33	599.68	0.2679	-1.1349	-0.8221	-0.529	0.26605
55	597.74	598.51	599.82	0.88586	596.56	597.52	598.61	0.97161	-1.3816	-0.98996	-0.4064	0.40436
100	596.68	598.89	599.78	1.2574	595.1	596.9	598.27	1.1413	-2.6123	-1.9894	-1.5146	0.46811
105	597.17	598.38	599.52	0.86327	594.91	596.5	597.66	1.0435	-2.3643	-1.8883	-1.0981	0.4968

Device Test: 21.4 _REF|VREF/VREF3/3/3/0/0/90.9/634//1.8//25C/@VREF_25C





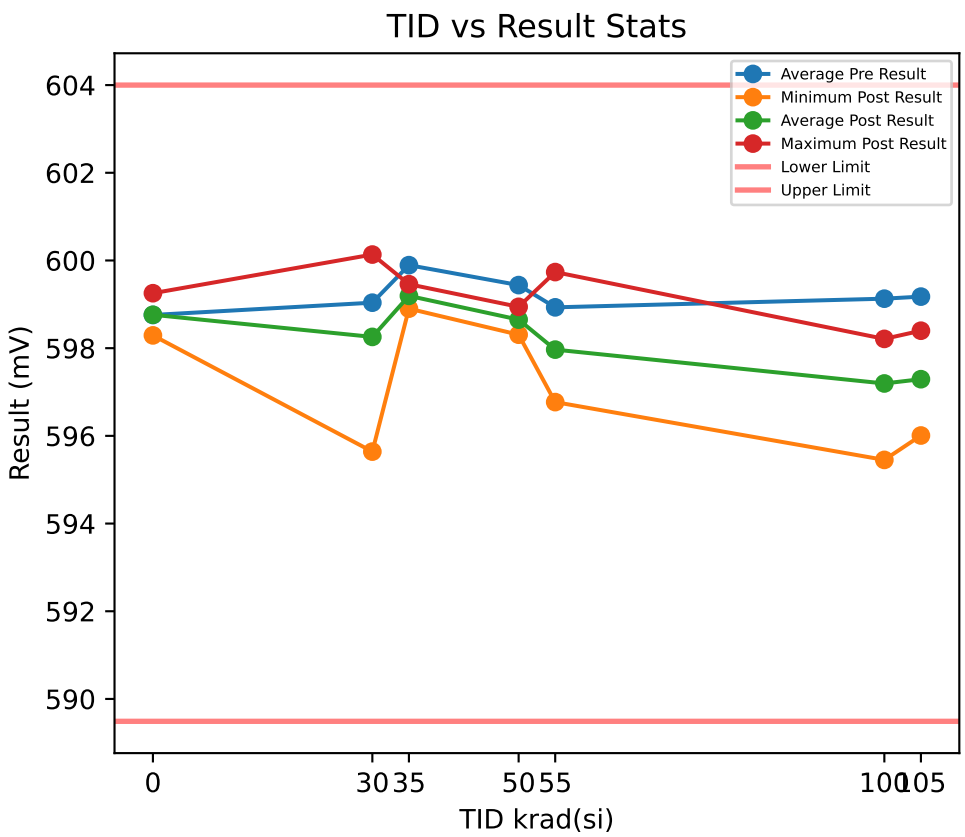
Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

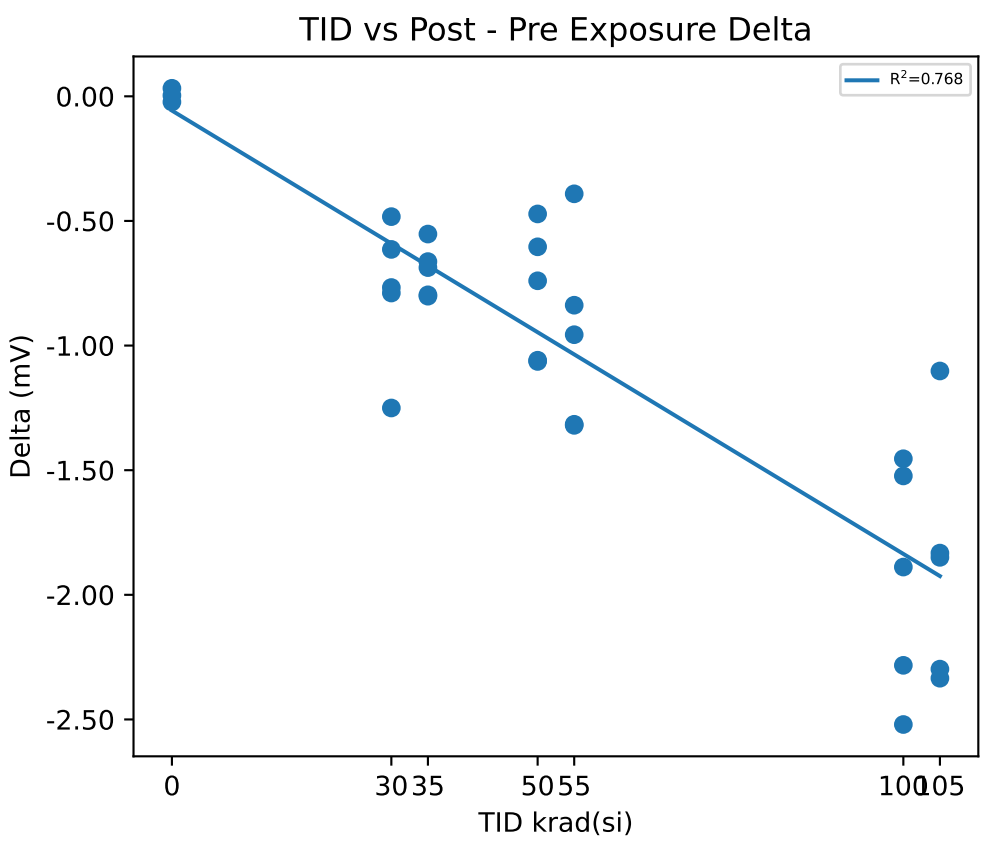
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.88	598.84	-0.0363
2	0	CU2	598.34	598.29	-0.0546
3	0	CU3	600.33	600.33	-0.0029
11	30	Unbiased-30krad	597.35	596.52	-0.8297
12	30	Unbiased-30krad	599.48	598.79	-0.6899
13	30	Unbiased-30krad	600.19	599.4	-0.7969
14	30	Unbiased-30krad	600.7	599.42	-1.2865
15	30	Unbiased-30krad	599.78	599.27	-0.5087
16	35	Biased-30krad	599.36	598.82	-0.5474
17	35	Biased-30krad	599.22	598.58	-0.64
18	35	Biased-30krad	599.59	598.79	-0.7974
19	35	Biased-30krad	599.47	598.63	-0.8373
20	35	Biased-30krad	600.53	599.85	-0.6816
30	50	Unbiased-50krad	600.21	599.63	-0.5802
31	50	Unbiased-50krad	599.19	598.11	-1.0784
32	50	Unbiased-50krad	600.56	599.41	-1.1438
33	50	Unbiased-50krad	600	599.24	-0.7583
34	50	Unbiased-50krad	599.28	598.66	-0.6166
40	55	Biased-50krad	598.17	596.83	-1.3431
41	55	Biased-50krad	600.46	599.16	-1.2949
42	55	Biased-50krad	598.48	597.41	-1.0742
43	55	Biased-50krad	599.45	598.59	-0.8624
44	55	Biased-50krad	600.56	600.09	-0.4664
45	100	Unbiased-100krad	599.89	597.63	-2.2632
46	100	Unbiased-100krad	599.72	598.26	-1.4664
47	100	Unbiased-100krad	599.77	597.21	-2.5603
48	100	Unbiased-100krad	597.13	595.51	-1.6197
49	100	Unbiased-100krad	600.74	598.87	-1.8711
50	105	Biased-100krad	600.01	598.87	-1.1433
51	105	Biased-100krad	599.43	597.09	-2.3355
52	105	Biased-100krad	598.12	596.27	-1.8472
53	105	Biased-100krad	598.47	596.14	-2.3274
54	105	Biased-100krad	599.62	597.8	-1.8115

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.34	599.18	600.33	1.0317	598.29	599.15	600.33	1.0578	-0.0546	-0.031267	-0.0029	0.026215
30	597.35	599.5	600.7	1.2857	596.52	598.68	599.42	1.231	-1.2865	-0.82234	-0.5087	0.28812
35	599.22	599.63	600.53	0.51953	598.58	598.93	599.85	0.52227	-0.8373	-0.70074	-0.5474	0.11786
50	599.19	599.85	600.56	0.59504	598.11	599.01	599.63	0.61891	-1.1438	-0.83546	-0.5802	0.2613
55	598.17	599.42	600.56	1.0973	596.83	598.42	600.09	1.3173	-1.3431	-1.0082	-0.4664	0.3583
100	597.13	599.45	600.74	1.3603	595.51	597.5	598.87	1.2733	-2.5603	-1.9561	-1.4664	0.45265
105	598.12	599.13	600.01	0.80095	596.14	597.24	598.87	1.1338	-2.3355	-1.893	-1.1433	0.4887

Device Test: 21.5 _REF|VREF/VREF4/3/3/0/0/90.9/634//1.8//25C/@VREF_25C





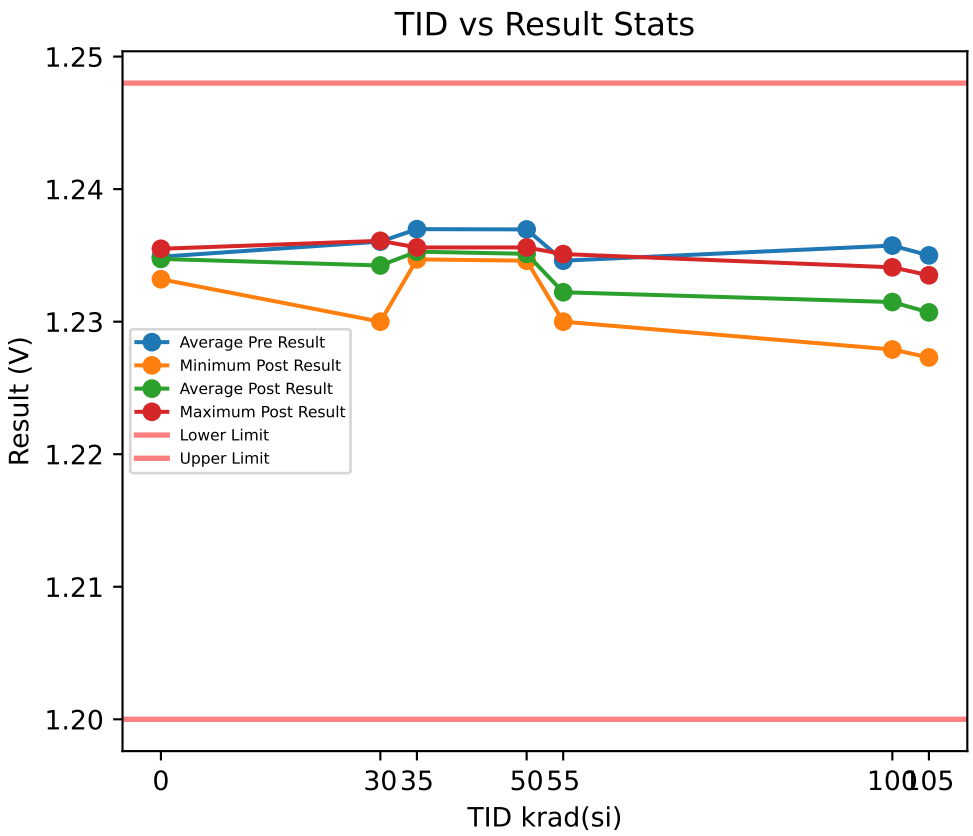
Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

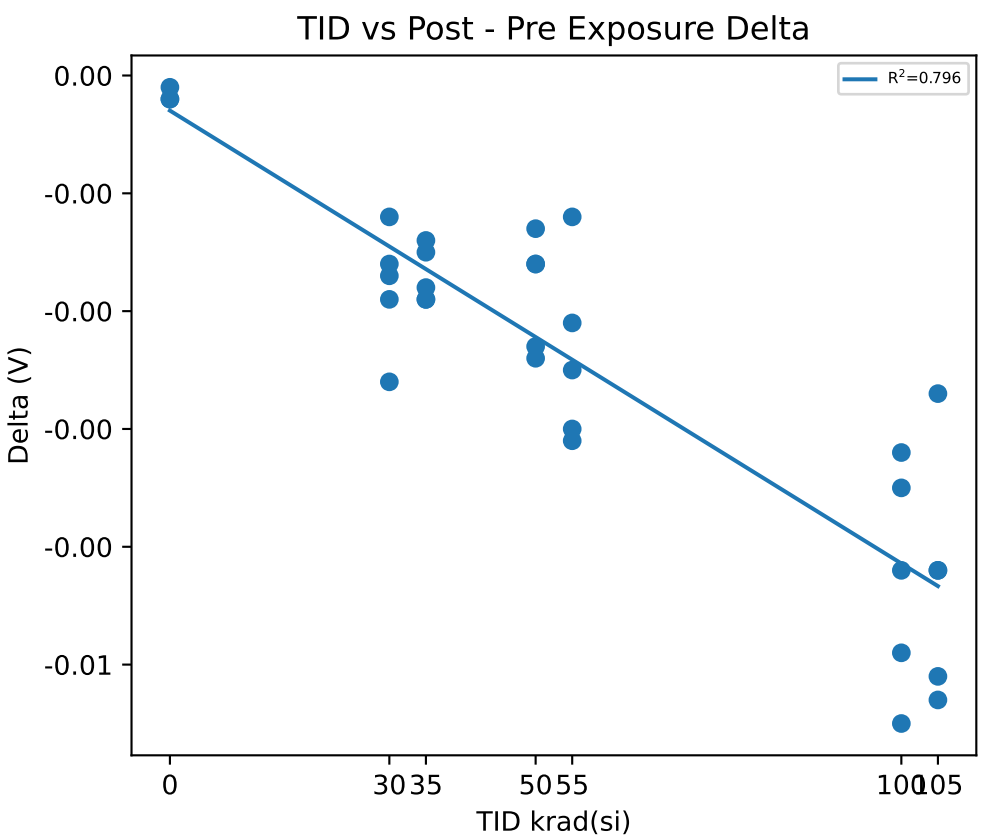
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.74	598.74	0.0034
2	0	CU2	598.31	598.29	-0.0227
3	0	CU3	599.22	599.25	0.0322
11	30	Unbiased-30krad	596.43	595.64	-0.7892
12	30	Unbiased-30krad	600.75	600.14	-0.6142
13	30	Unbiased-30krad	600.54	599.78	-0.7671
14	30	Unbiased-30krad	598.51	597.26	-1.2504
15	30	Unbiased-30krad	598.96	598.47	-0.4827
16	35	Biased-30krad	599.45	598.9	-0.5526
17	35	Biased-30krad	599.97	599.3	-0.6631
18	35	Biased-30krad	600.26	599.46	-0.7964
19	35	Biased-30krad	599.76	598.95	-0.8019
20	35	Biased-30krad	600.03	599.35	-0.6872
30	50	Unbiased-50krad	599.39	598.91	-0.4719
31	50	Unbiased-50krad	599.37	598.31	-1.0588
32	50	Unbiased-50krad	599.49	598.43	-1.0637
33	50	Unbiased-50krad	599.4	598.66	-0.7401
34	50	Unbiased-50krad	599.55	598.94	-0.6038
40	55	Biased-50krad	598.09	596.77	-1.3158
41	55	Biased-50krad	600.1	598.78	-1.3201
42	55	Biased-50krad	597.94	596.99	-0.9564
43	55	Biased-50krad	598.4	597.56	-0.8381
44	55	Biased-50krad	600.13	599.74	-0.3912
45	100	Unbiased-100krad	599.99	597.71	-2.2829
46	100	Unbiased-100krad	599.67	598.21	-1.4541
47	100	Unbiased-100krad	599.27	596.75	-2.5203
48	100	Unbiased-100krad	596.97	595.45	-1.523
49	100	Unbiased-100krad	599.74	597.85	-1.8886
50	105	Biased-100krad	599.5	598.4	-1.102
51	105	Biased-100krad	600.29	597.96	-2.3346
52	105	Biased-100krad	597.86	596.01	-1.8496
53	105	Biased-100krad	598.49	596.19	-2.2981
54	105	Biased-100krad	599.74	597.91	-1.8326

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.31	598.76	599.22	0.45377	598.29	598.76	599.25	0.48123	-0.0227	0.0043	0.0322	0.027461
30	596.43	599.04	600.75	1.7524	595.64	598.26	600.14	1.8525	-1.2504	-0.78072	-0.4827	0.29043
35	599.45	599.89	600.26	0.3033	598.9	599.19	599.46	0.24942	-0.8019	-0.70024	-0.5526	0.1036
50	599.37	599.44	599.55	0.077645	598.31	598.65	598.94	0.28352	-1.0637	-0.78766	-0.4719	0.26715
55	597.94	598.93	600.13	1.0933	596.77	597.97	599.74	1.2605	-1.3201	-0.96432	-0.3912	0.38554
100	596.97	599.13	599.99	1.2313	595.45	597.19	598.21	1.1139	-2.5203	-1.9338	-1.4541	0.4655
105	597.86	599.18	600.29	0.98575	596.01	597.29	598.4	1.1083	-2.3346	-1.8834	-1.102	0.49746

Device Test: 22.1 _REF|REFCAP/REFCAP/7/7/0/0/90.9/634//1.8//25C/@VREFCAP





Test Results (Lower Limit = 1.2, Upper Limit = 1.248 (V))

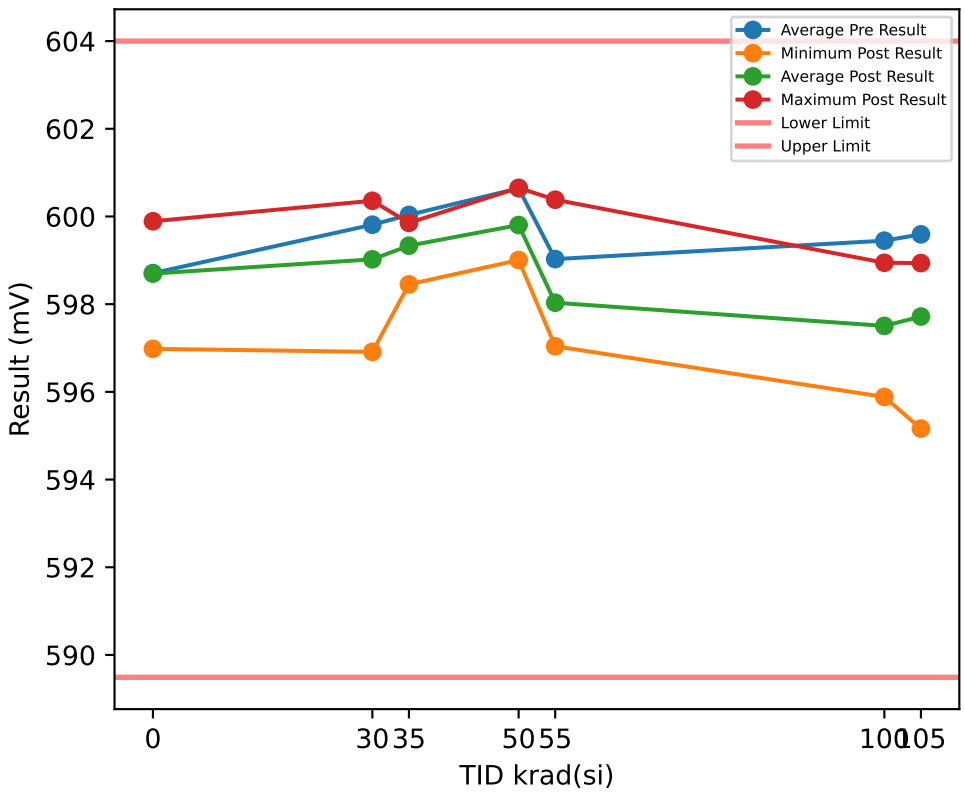
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.2357	1.2355	-0.0002
2	0	CU2	1.2334	1.2332	-0.0002
3	0	CU3	1.2356	1.2355	-0.0001
11	30	Unbiased-30krad	1.2319	1.23	-0.0019
12	30	Unbiased-30krad	1.2377	1.2361	-0.0016
13	30	Unbiased-30krad	1.2372	1.2355	-0.0017
14	30	Unbiased-30krad	1.2368	1.2342	-0.0026
15	30	Unbiased-30krad	1.2366	1.2354	-0.0012
16	35	Biased-30krad	1.2368	1.2354	-0.0014
17	35	Biased-30krad	1.2362	1.2347	-0.0015
18	35	Biased-30krad	1.2372	1.2353	-0.0019
19	35	Biased-30krad	1.2375	1.2356	-0.0019
20	35	Biased-30krad	1.2372	1.2354	-0.0018
30	50	Unbiased-50krad	1.2367	1.2354	-0.0013
31	50	Unbiased-50krad	1.2369	1.2346	-0.0023
32	50	Unbiased-50krad	1.238	1.2356	-0.0024
33	50	Unbiased-50krad	1.2368	1.2352	-0.0016
34	50	Unbiased-50krad	1.2364	1.2348	-0.0016
40	55	Biased-50krad	1.2342	1.2311	-0.0031
41	55	Biased-50krad	1.2361	1.2331	-0.003
42	55	Biased-50krad	1.2325	1.23	-0.0025
43	55	Biased-50krad	1.2339	1.2318	-0.0021
44	55	Biased-50krad	1.2363	1.2351	-0.0012
45	100	Unbiased-100krad	1.2362	1.2313	-0.0049
46	100	Unbiased-100krad	1.2373	1.2341	-0.0032
47	100	Unbiased-100krad	1.2373	1.2318	-0.0055
48	100	Unbiased-100krad	1.2314	1.2279	-0.0035
49	100	Unbiased-100krad	1.2365	1.2323	-0.0042
50	105	Biased-100krad	1.2362	1.2335	-0.0027
51	105	Biased-100krad	1.2375	1.2322	-0.0053
52	105	Biased-100krad	1.2342	1.23	-0.0042
53	105	Biased-100krad	1.2324	1.2273	-0.0051
54	105	Biased-100krad	1.2347	1.2305	-0.0042

Test Statistics (V)

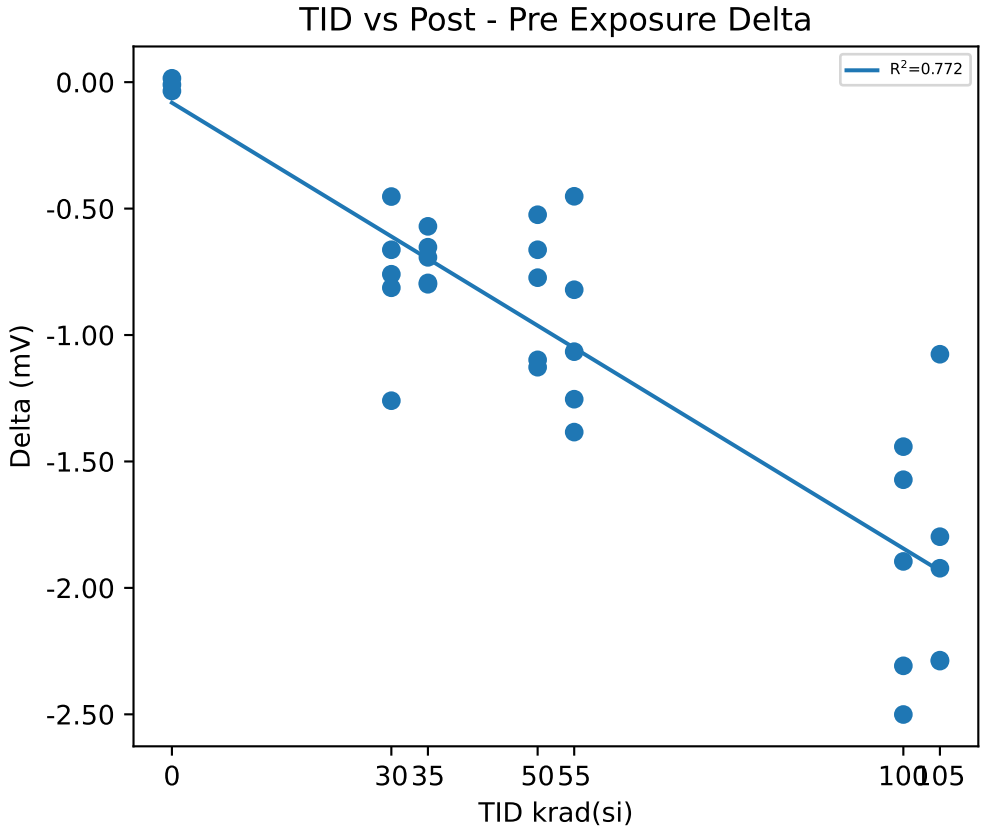
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2334	1.2349	1.2357	0.0013	1.2332	1.2347	1.2355	0.0013279	-0.0002	-0.00016667	-0.0001	5.7735e-05
30	1.2319	1.236	1.2377	0.0023522	1.23	1.2342	1.2361	0.0024684	-0.0026	-0.0018	-0.0012	0.00051478
35	1.2362	1.237	1.2375	0.000502	1.2347	1.2353	1.2356	0.00034205	-0.0019	-0.0017	-0.0014	0.00023452
50	1.2364	1.237	1.238	0.00061074	1.2346	1.2351	1.2356	0.00041473	-0.0024	-0.00184	-0.0013	0.0004827
55	1.2325	1.2346	1.2363	0.0015969	1.23	1.2322	1.2351	0.0019639	-0.0031	-0.00238	-0.0012	0.00077266
100	1.2314	1.2357	1.2373	0.0024745	1.2279	1.2315	1.2341	0.0022632	-0.0055	-0.00426	-0.0032	0.00095551
105	1.2324	1.235	1.2375	0.0019481	1.2273	1.2307	1.2335	0.0023548	-0.0053	-0.0043	-0.0027	0.0010271

Device Test: 22.2 _REF|VREF/VREF1/7/7/0/0/90.9/634//1.8//25C/@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

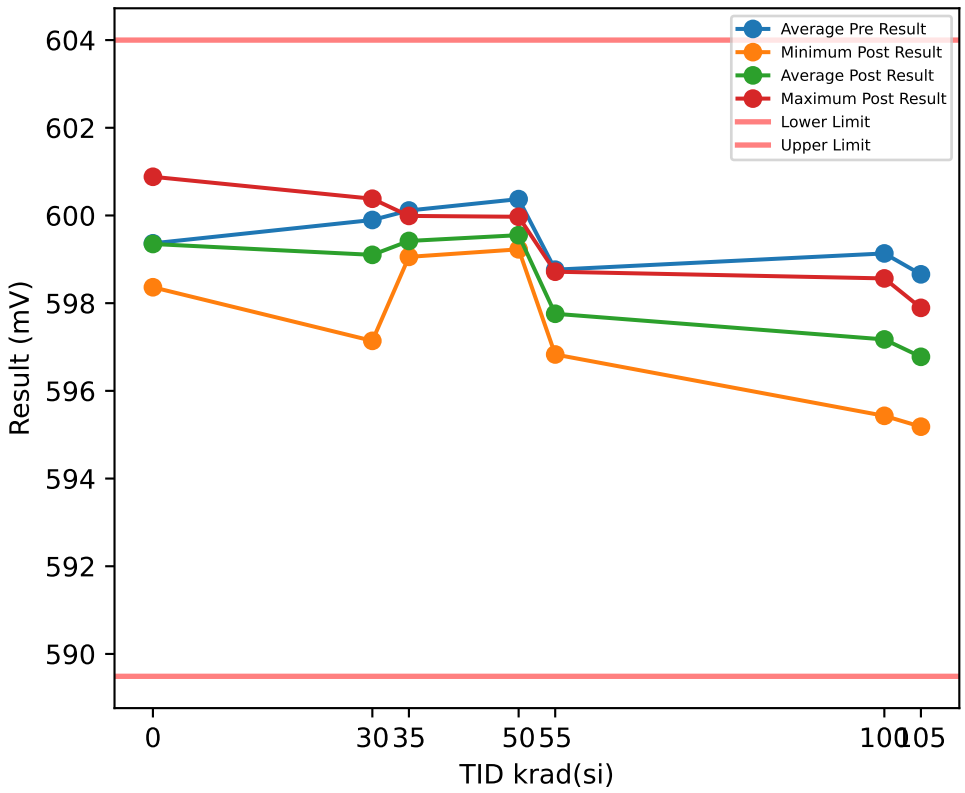
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.93	599.89	-0.035
2	0	CU2	596.99	596.98	-0.01
3	0	CU3	599.21	599.22	0.0153
11	30	Unbiased-30krad	598	597.18	-0.8131
12	30	Unbiased-30krad	600.98	600.32	-0.6628
13	30	Unbiased-30krad	601.1	600.34	-0.7596
14	30	Unbiased-30krad	598.17	596.91	-1.2597
15	30	Unbiased-30krad	600.81	600.36	-0.4524
16	35	Biased-30krad	600.13	599.56	-0.5702
17	35	Biased-30krad	600.25	599.6	-0.6527
18	35	Biased-30krad	599.25	598.45	-0.7939
19	35	Biased-30krad	600.65	599.85	-0.7993
20	35	Biased-30krad	599.89	599.2	-0.6928
30	50	Unbiased-50krad	601.18	600.65	-0.5243
31	50	Unbiased-50krad	600.62	599.52	-1.0982
32	50	Unbiased-50krad	601.27	600.15	-1.1273
33	50	Unbiased-50krad	600.47	599.7	-0.7732
34	50	Unbiased-50krad	599.67	599.01	-0.6628
40	55	Biased-50krad	598.82	597.44	-1.3839
41	55	Biased-50krad	599.14	597.88	-1.2538
42	55	Biased-50krad	598.11	597.04	-1.0658
43	55	Biased-50krad	598.24	597.42	-0.8209
44	55	Biased-50krad	600.83	600.38	-0.4514
45	100	Unbiased-100krad	599.37	597.06	-2.3082
46	100	Unbiased-100krad	600.39	598.94	-1.4414
47	100	Unbiased-100krad	600.1	597.6	-2.5007
48	100	Unbiased-100krad	597.46	595.88	-1.5722
49	100	Unbiased-100krad	599.93	598.03	-1.8953
50	105	Biased-100krad	600.01	598.94	-1.076
51	105	Biased-100krad	600.81	598.52	-2.2858
52	105	Biased-100krad	599.91	597.99	-1.9223
53	105	Biased-100krad	597.45	595.16	-2.2895
54	105	Biased-100krad	599.78	597.99	-1.7975

Test Statistics (mV)

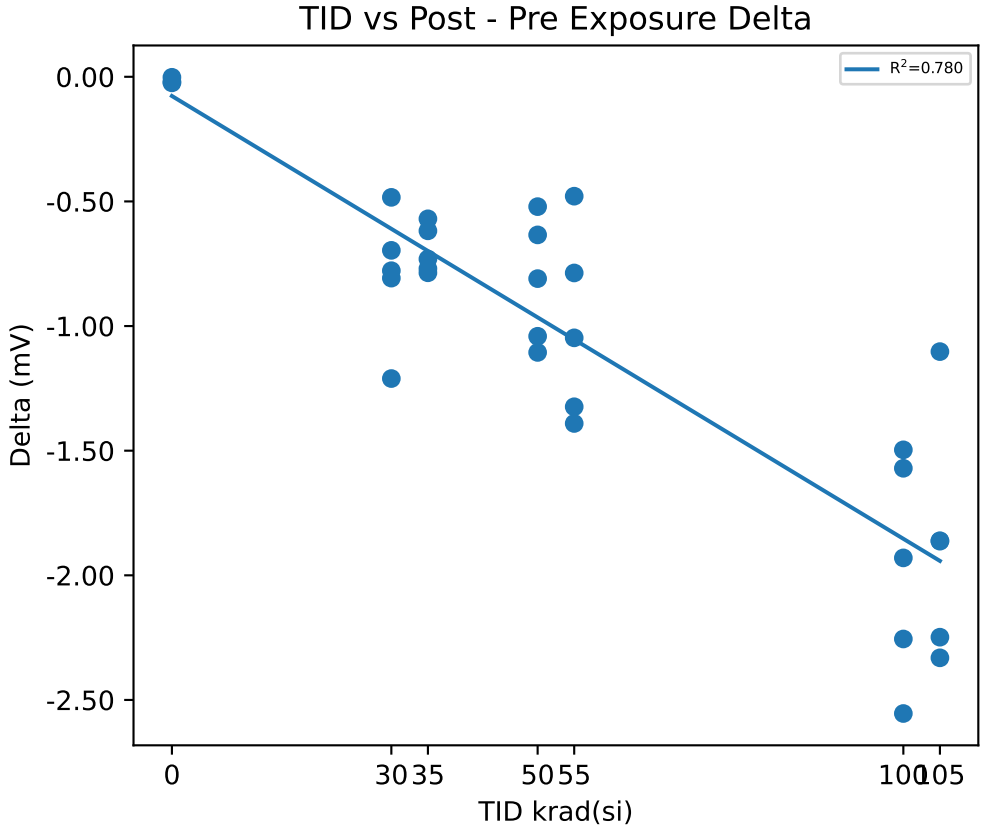
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.99	598.71	599.93	1.5294	596.98	598.7	599.89	1.5238	-0.035	-0.0099	0.0153	0.02515
30	598	599.81	601.1	1.5824	596.91	599.02	600.36	1.8058	-1.2597	-0.78952	-0.4524	0.29674
35	599.25	600.04	600.65	0.51995	598.45	599.33	599.85	0.54515	-0.7993	-0.70178	-0.5702	0.09721
50	599.67	600.64	601.27	0.64428	599.01	599.81	600.65	0.62521	-1.1273	-0.83716	-0.5243	0.26678
55	598.11	599.03	600.83	1.0939	597.04	598.03	600.38	1.3472	-1.3839	-0.99516	-0.4514	0.37049
100	597.46	599.45	600.39	1.1736	595.88	597.5	598.94	1.138	-2.5007	-1.9436	-1.4414	0.4571
105	597.45	599.59	600.81	1.2619	595.16	597.72	598.94	1.4839	-2.2895	-1.8742	-1.076	0.49679

Device Test: 22.3 _REF|VREF/VREF2/7/7/0/0/90.9/634//1.8//25C/@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

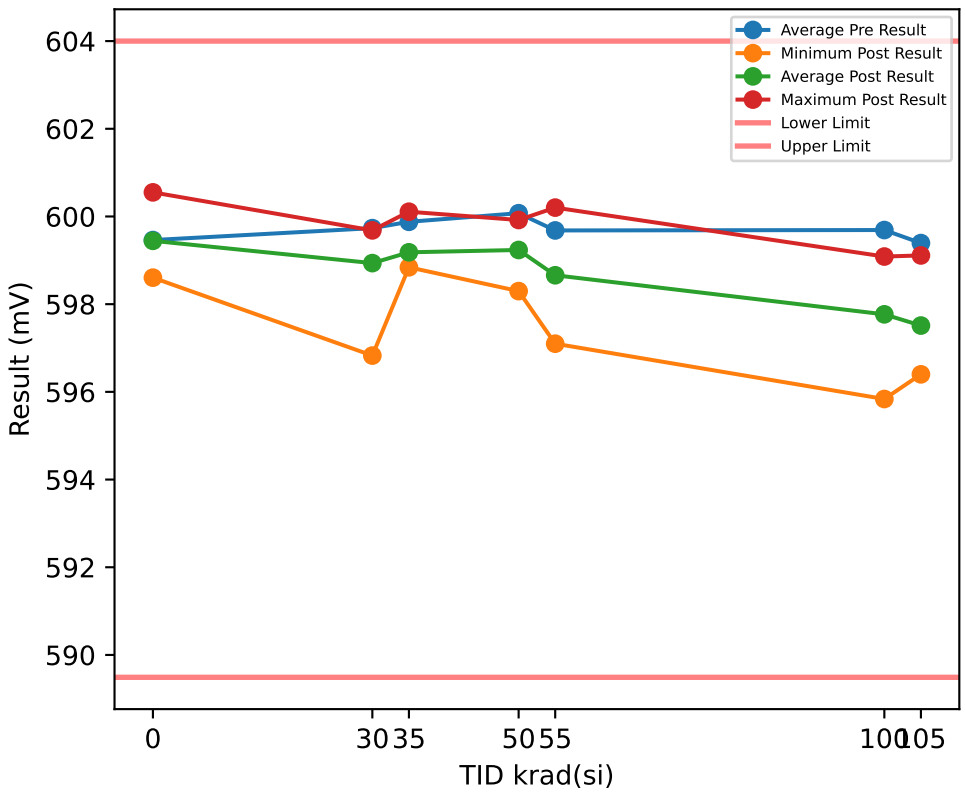
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.38	598.36	-0.0201
2	0	CU2	598.83	598.8	-0.0243
3	0	CU3	600.88	600.88	-0.002
11	30	Unbiased-30krad	597.95	597.14	-0.8077
12	30	Unbiased-30krad	601.08	600.38	-0.6963
13	30	Unbiased-30krad	599.79	599.01	-0.7779
14	30	Unbiased-30krad	600.12	598.91	-1.2106
15	30	Unbiased-30krad	600.55	600.07	-0.4837
16	35	Biased-30krad	599.68	599.11	-0.5698
17	35	Biased-30krad	600.03	599.41	-0.618
18	35	Biased-30krad	600.76	599.99	-0.7696
19	35	Biased-30krad	599.84	599.06	-0.7863
20	35	Biased-30krad	600.26	599.53	-0.7311
30	50	Unbiased-50krad	600.49	599.97	-0.5209
31	50	Unbiased-50krad	600.35	599.31	-1.041
32	50	Unbiased-50krad	600.8	599.69	-1.1058
33	50	Unbiased-50krad	600.37	599.56	-0.8097
34	50	Unbiased-50krad	599.86	599.23	-0.6343
40	55	Biased-50krad	598.22	596.83	-1.3908
41	55	Biased-50krad	600.04	598.72	-1.3238
42	55	Biased-50krad	598.06	597.01	-1.0473
43	55	Biased-50krad	598.31	597.52	-0.787
44	55	Biased-50krad	599.19	598.71	-0.479
45	100	Unbiased-100krad	599.57	597.31	-2.2554
46	100	Unbiased-100krad	600.06	598.56	-1.4966
47	100	Unbiased-100krad	599.73	597.18	-2.5544
48	100	Unbiased-100krad	597	595.43	-1.5706
49	100	Unbiased-100krad	599.31	597.38	-1.9301
50	105	Biased-100krad	599	597.89	-1.1025
51	105	Biased-100krad	599.81	597.48	-2.331
52	105	Biased-100krad	598.39	596.53	-1.8613
53	105	Biased-100krad	597.43	595.18	-2.2482
54	105	Biased-100krad	598.65	596.79	-1.863

Test Statistics (mV)

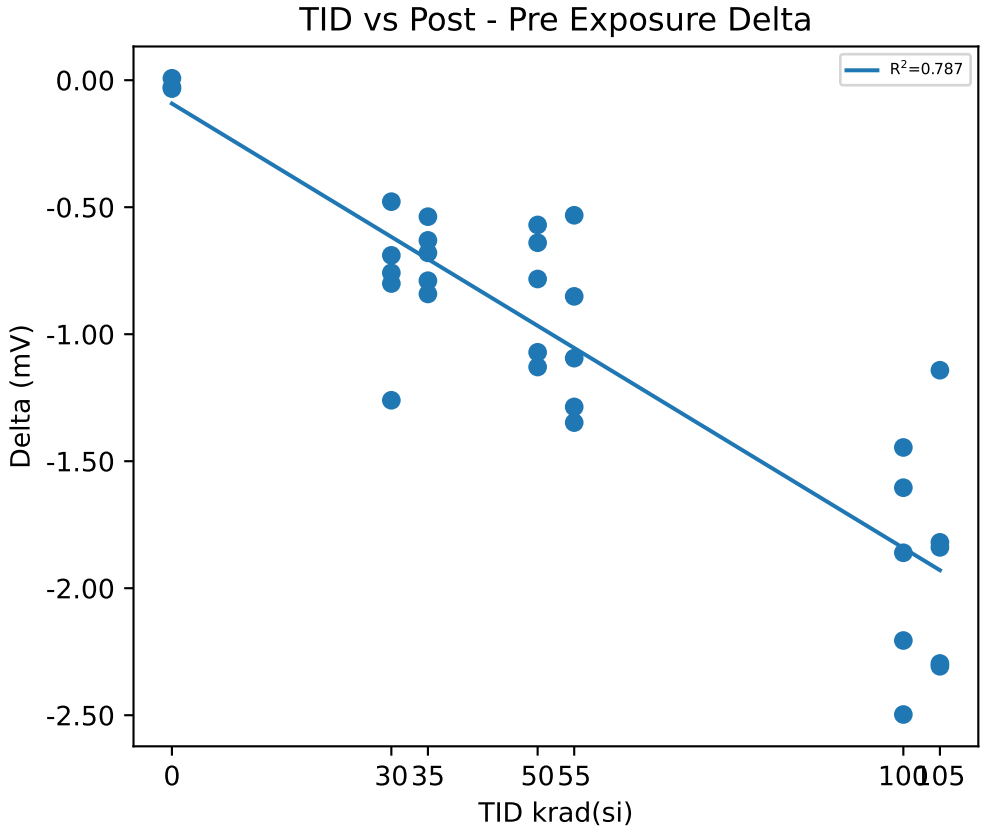
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.38	599.37	600.88	1.3345	598.36	599.35	600.88	1.3457	-0.0243	-0.015467	-0.002	0.01185
30	597.95	599.9	601.08	1.192	597.14	599.1	600.38	1.2709	-1.2106	-0.79524	-0.4837	0.26449
35	599.68	600.11	600.76	0.42098	599.06	599.42	599.99	0.37635	-0.7863	-0.69496	-0.5698	0.095927
50	599.86	600.37	600.8	0.33682	599.23	599.55	599.97	0.29945	-1.1058	-0.82234	-0.5209	0.25226
55	598.06	598.76	600.04	0.83872	596.83	597.76	598.72	0.90896	-1.3908	-1.0056	-0.479	0.37963
100	597	599.13	600.06	1.2233	595.43	597.17	598.56	1.1218	-2.5544	-1.9614	-1.4966	0.4494
105	597.43	598.66	599.81	0.8698	595.18	596.78	597.89	1.0422	-2.331	-1.8812	-1.1025	0.48583

Device Test: 22.4 _REF|VREF/VREF3/7/7/0/0/90.9/634//1.8//25C/@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

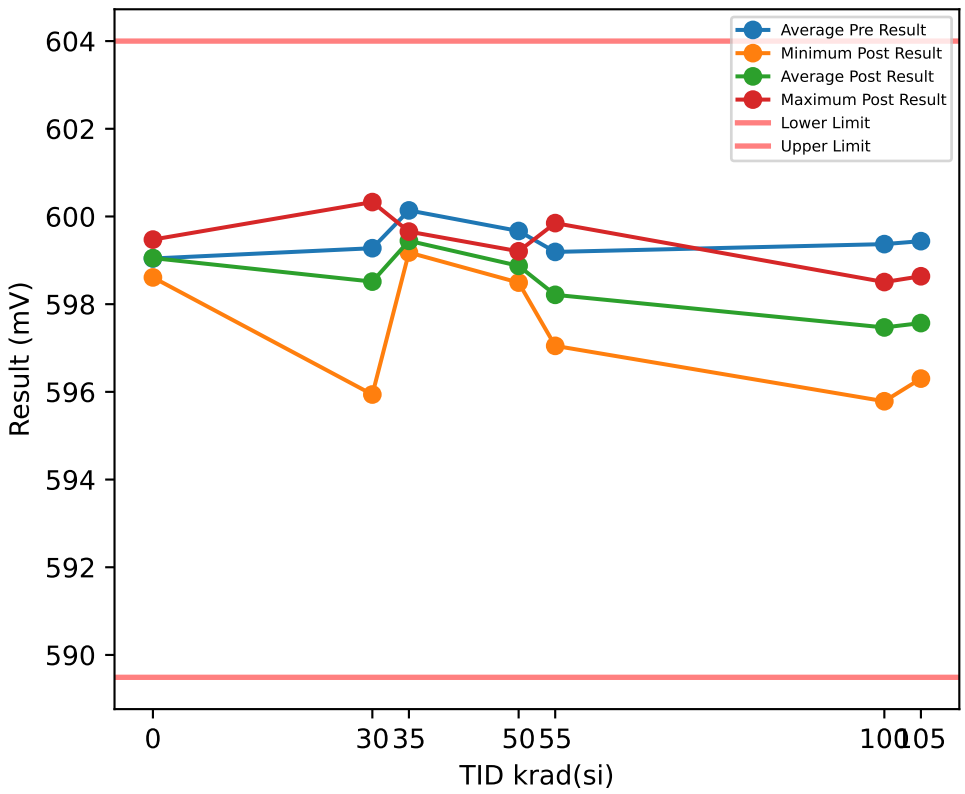
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.21	599.18	-0.0331
2	0	CU2	598.63	598.6	-0.0269
3	0	CU3	600.54	600.55	0.0075
11	30	Unbiased-30krad	597.63	596.83	-0.8005
12	30	Unbiased-30krad	599.67	598.98	-0.6896
13	30	Unbiased-30krad	600.41	599.66	-0.7583
14	30	Unbiased-30krad	600.94	599.68	-1.2601
15	30	Unbiased-30krad	600.01	599.54	-0.4782
16	35	Biased-30krad	599.67	599.14	-0.5373
17	35	Biased-30krad	599.49	598.86	-0.6306
18	35	Biased-30krad	599.76	598.97	-0.7894
19	35	Biased-30krad	599.68	598.84	-0.8415
20	35	Biased-30krad	600.79	600.11	-0.6798
30	50	Unbiased-50krad	600.49	599.92	-0.5698
31	50	Unbiased-50krad	599.37	598.3	-1.0712
32	50	Unbiased-50krad	600.8	599.67	-1.1292
33	50	Unbiased-50krad	600.18	599.4	-0.7827
34	50	Unbiased-50krad	599.53	598.89	-0.6399
40	55	Biased-50krad	598.45	597.1	-1.348
41	55	Biased-50krad	600.68	599.39	-1.2863
42	55	Biased-50krad	598.81	597.71	-1.0943
43	55	Biased-50krad	599.74	598.89	-0.8511
44	55	Biased-50krad	600.73	600.2	-0.5318
45	100	Unbiased-100krad	600.06	597.86	-2.2059
46	100	Unbiased-100krad	600	598.55	-1.4459
47	100	Unbiased-100krad	600.01	597.51	-2.4972
48	100	Unbiased-100krad	597.44	595.84	-1.6043
49	100	Unbiased-100krad	600.95	599.09	-1.8605
50	105	Biased-100krad	600.25	599.11	-1.1418
51	105	Biased-100krad	599.71	597.41	-2.2963
52	105	Biased-100krad	598.4	596.56	-1.8392
53	105	Biased-100krad	598.71	596.4	-2.3074
54	105	Biased-100krad	599.89	598.07	-1.8194

Test Statistics (mV)

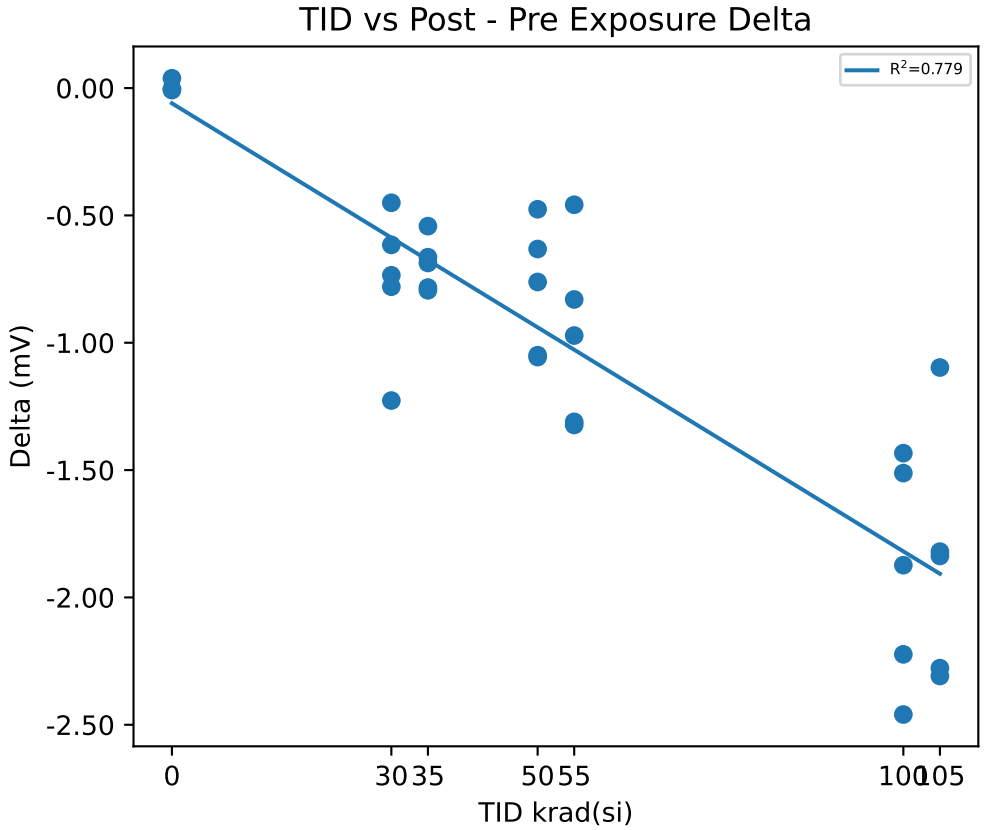
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.63	599.46	600.54	0.9797	598.6	599.44	600.55	0.9995	-0.0331	-0.0175	0.0075	0.021871
30	597.63	599.73	600.94	1.269	596.83	598.94	599.68	1.2127	-1.2601	-0.79734	-0.4782	0.28685
35	599.49	599.88	600.79	0.51853	598.84	599.18	600.11	0.53076	-0.8415	-0.69572	-0.5373	0.12208
50	599.37	600.07	600.8	0.61232	598.3	599.24	599.92	0.64823	-1.1292	-0.83856	-0.5698	0.2517
55	598.45	599.68	600.73	1.0485	597.1	598.66	600.2	1.2552	-1.348	-1.0223	-0.5318	0.33573
100	597.44	599.69	600.95	1.3199	595.84	597.77	599.09	1.2405	-2.4972	-1.9228	-1.4459	0.43094
105	598.4	599.39	600.25	0.79749	596.4	597.51	599.11	1.1204	-2.3074	-1.8808	-1.1418	0.47599

Device Test: 22.5 _REF|VREF/VREF4/7/7/0/0/90.9/634//1.8//25C/@VREF_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



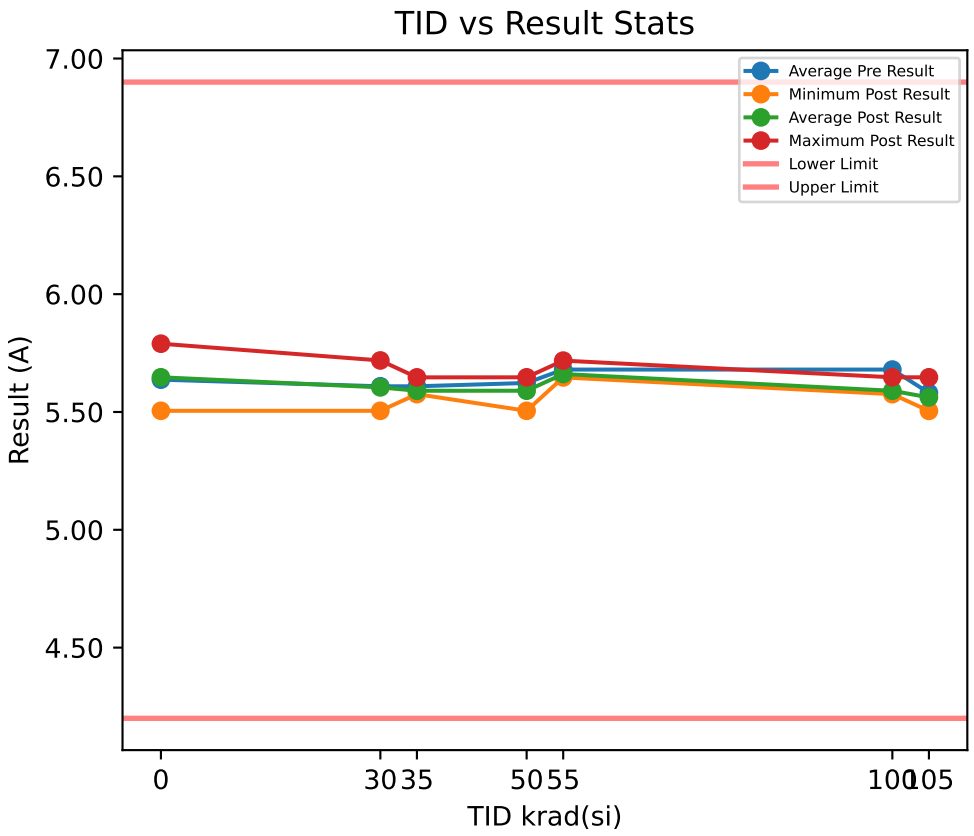
Test Results (Lower Limit = 589.49, Upper Limit = 604.0 (mV))

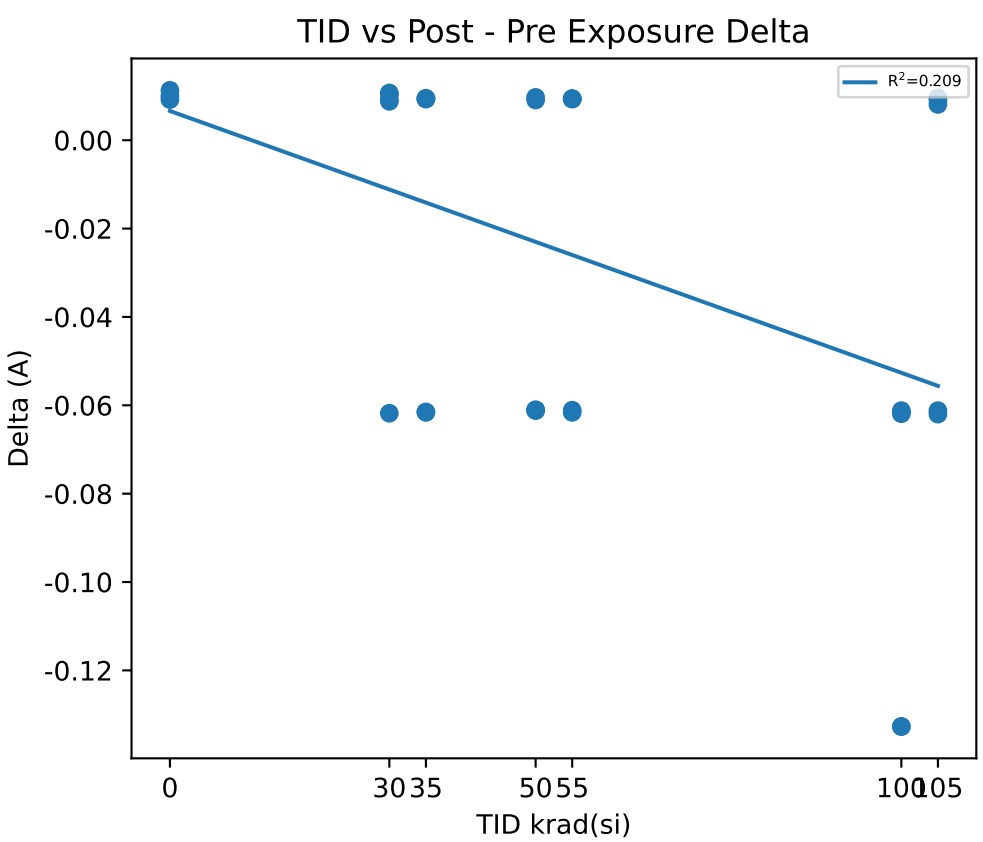
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.07	599.07	-0.0025
2	0	CU2	598.62	598.61	-0.008
3	0	CU3	599.43	599.47	0.0384
11	30	Unbiased-30krad	596.72	595.94	-0.78
12	30	Unbiased-30krad	600.94	600.33	-0.6157
13	30	Unbiased-30krad	600.77	600.04	-0.735
14	30	Unbiased-30krad	598.76	597.53	-1.227
15	30	Unbiased-30krad	599.19	598.74	-0.4503
16	35	Biased-30krad	599.75	599.21	-0.5422
17	35	Biased-30krad	600.24	599.58	-0.6641
18	35	Biased-30krad	600.44	599.66	-0.7833
19	35	Biased-30krad	599.97	599.18	-0.794
20	35	Biased-30krad	600.29	599.6	-0.6867
30	50	Unbiased-50krad	599.68	599.21	-0.4758
31	50	Unbiased-50krad	599.55	598.49	-1.0563
32	50	Unbiased-50krad	599.73	598.68	-1.0489
33	50	Unbiased-50krad	599.58	598.82	-0.7613
34	50	Unbiased-50krad	599.8	599.17	-0.6319
40	55	Biased-50krad	598.37	597.05	-1.3229
41	55	Biased-50krad	600.32	599.01	-1.3106
42	55	Biased-50krad	598.27	597.29	-0.9717
43	55	Biased-50krad	598.69	597.86	-0.83
44	55	Biased-50krad	600.31	599.85	-0.4581
45	100	Unbiased-100krad	600.16	597.93	-2.2235
46	100	Unbiased-100krad	599.94	598.5	-1.4336
47	100	Unbiased-100krad	599.52	597.06	-2.4597
48	100	Unbiased-100krad	597.3	595.79	-1.5118
49	100	Unbiased-100krad	599.94	598.07	-1.8734
50	105	Biased-100krad	599.73	598.64	-1.0972
51	105	Biased-100krad	600.58	598.27	-2.3085
52	105	Biased-100krad	598.14	596.3	-1.8371
53	105	Biased-100krad	598.73	596.45	-2.2777
54	105	Biased-100krad	600.01	598.19	-1.8201

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.62	599.04	599.43	0.40909	598.61	599.05	599.47	0.43172	-0.008	0.0093	0.0384	0.025351
30	596.72	599.28	600.94	1.7201	595.94	598.51	600.33	1.8208	-1.227	-0.7616	-0.4503	0.28976
35	599.75	600.14	600.44	0.27298	599.18	599.44	599.66	0.22973	-0.794	-0.69406	-0.5422	0.10243
50	599.55	599.67	599.8	0.1055	598.49	598.87	599.21	0.30944	-1.0563	-0.79484	-0.4758	0.25611
55	598.27	599.19	600.32	1.038	597.05	598.21	599.85	1.1877	-1.3229	-0.97866	-0.4581	0.36118
100	597.3	599.37	600.16	1.1813	595.79	597.47	598.5	1.0781	-2.4597	-1.9004	-1.4336	0.44352
105	598.14	599.44	600.58	0.98837	596.3	597.57	598.64	1.1038	-2.3085	-1.8681	-1.0972	0.48971

Device Test: 26.2 _ILIM_HS|HS_Sourcing/SW1/3/3///90.9/634//1.8///@HIGH_SIDE_OC





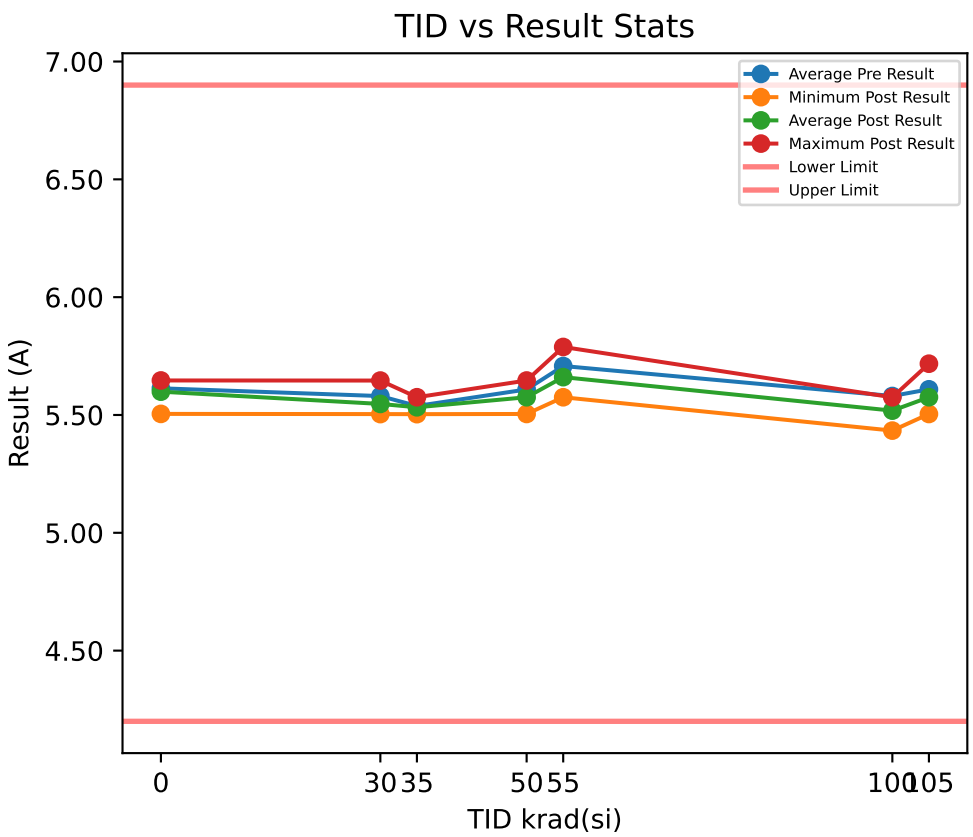
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

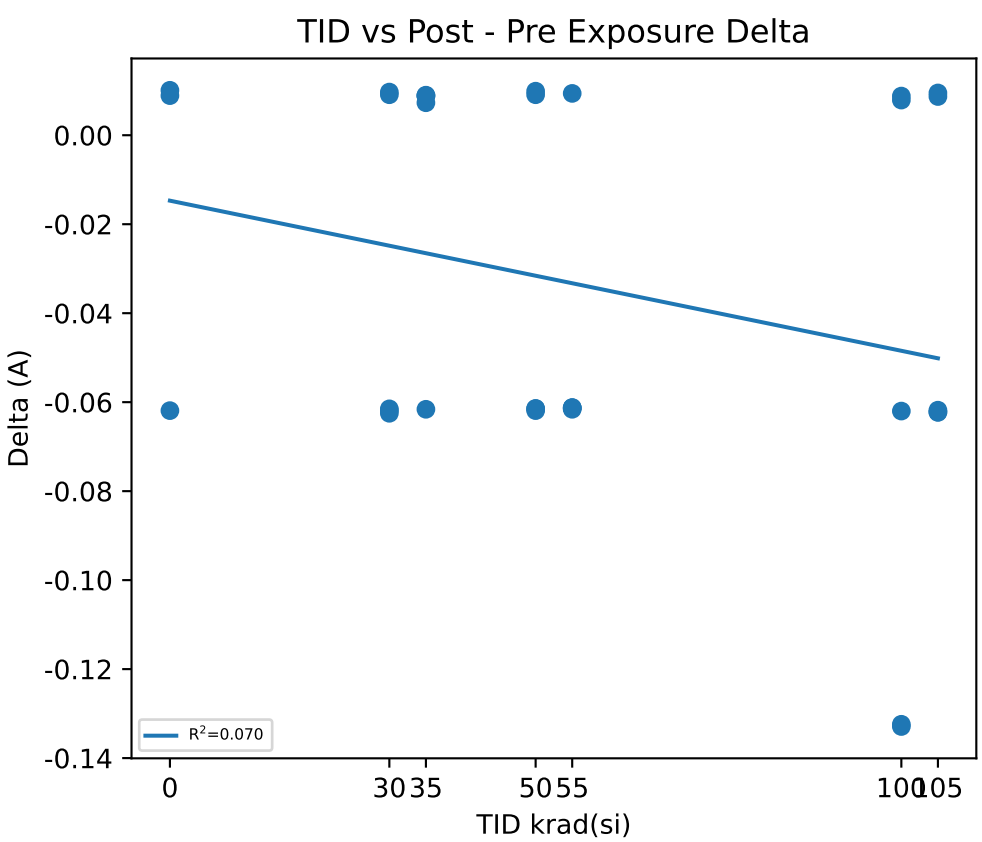
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7785	5.7898	0.0113
2	0	CU2	5.4958	5.505	0.0092
3	0	CU3	5.6371	5.6471	0.01
11	30	Unbiased-30krad	5.708	5.7187	0.0107
12	30	Unbiased-30krad	5.6372	5.6475	0.0103
13	30	Unbiased-30krad	5.5665	5.5757	0.0092
14	30	Unbiased-30krad	5.6372	5.5754	-0.0618
15	30	Unbiased-30krad	5.4962	5.505	0.0088
16	35	Biased-30krad	5.6374	5.5758	-0.0616
17	35	Biased-30krad	5.5663	5.5757	0.0094
18	35	Biased-30krad	5.5667	5.576	0.0093
19	35	Biased-30krad	5.6374	5.6469	0.0095
20	35	Biased-30krad	5.6372	5.5757	-0.0615
30	50	Unbiased-50krad	5.6374	5.6471	0.0097
31	50	Unbiased-50krad	5.7081	5.6471	-0.061
32	50	Unbiased-50krad	5.6371	5.576	-0.0611
33	50	Unbiased-50krad	5.5662	5.505	-0.0612
34	50	Unbiased-50krad	5.5667	5.5758	0.0091
40	55	Biased-50krad	5.6374	5.6468	0.0094
41	55	Biased-50krad	5.6374	5.6467	0.0093
42	55	Biased-50krad	5.7791	5.718	-0.0611
43	55	Biased-50krad	5.7085	5.6469	-0.0616
44	55	Biased-50krad	5.6375	5.6469	0.0094
45	100	Unbiased-100krad	5.7085	5.5758	-0.1327
46	100	Unbiased-100krad	5.6372	5.5756	-0.0616
47	100	Unbiased-100krad	5.7084	5.6472	-0.0612
48	100	Unbiased-100krad	5.6375	5.5756	-0.0619
49	100	Unbiased-100krad	5.7084	5.5757	-0.1327
50	105	Biased-100krad	5.5669	5.5049	-0.062
51	105	Biased-100krad	5.6376	5.6472	0.0096
52	105	Biased-100krad	5.5669	5.5761	0.0092
53	105	Biased-100krad	5.6374	5.5762	-0.0612
54	105	Biased-100krad	5.4966	5.5047	0.0081

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4958	5.6371	5.7785	0.14135	5.505	5.6473	5.7898	0.1424	0.0092	0.010167	0.0113	0.0010599
30	5.4962	5.609	5.708	0.080501	5.505	5.6045	5.7187	0.081344	-0.0618	-0.00456	0.0107	0.032008
35	5.5663	5.609	5.6374	0.038797	5.5757	5.59	5.6469	0.031797	-0.0616	-0.01898	0.0095	0.038861
50	5.5662	5.6231	5.7081	0.059254	5.505	5.5902	5.6471	0.059463	-0.0612	-0.0329	0.0097	0.038615
55	5.6374	5.68	5.7791	0.063381	5.6467	5.6611	5.718	0.031831	-0.0616	-0.01892	0.0094	0.038734
100	5.6372	5.68	5.7085	0.038934	5.5756	5.59	5.6472	0.031987	-0.1327	-0.09002	-0.0612	0.038962
105	5.4966	5.5811	5.6376	0.058961	5.5047	5.5618	5.6472	0.059588	-0.062	-0.01926	0.0096	0.038656

Device Test: 26.3 _ILIM_HS|HS_Sourcing/SW2/3/3///90.9/634//1.8///@HIGH_SIDE_OC





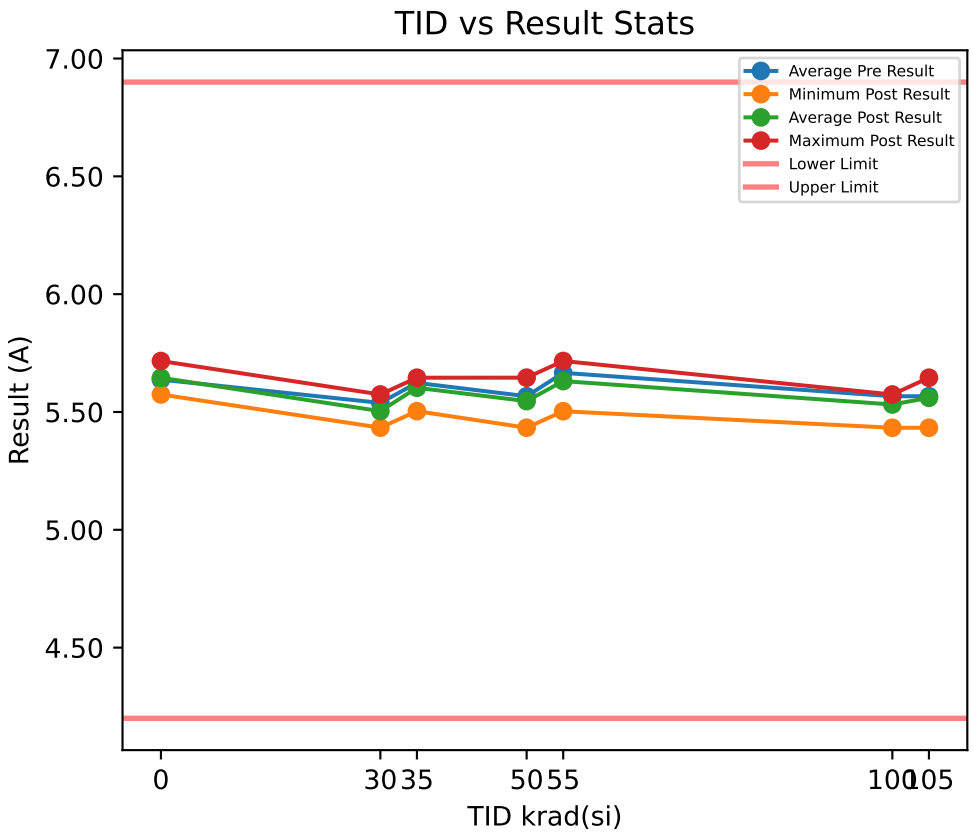
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

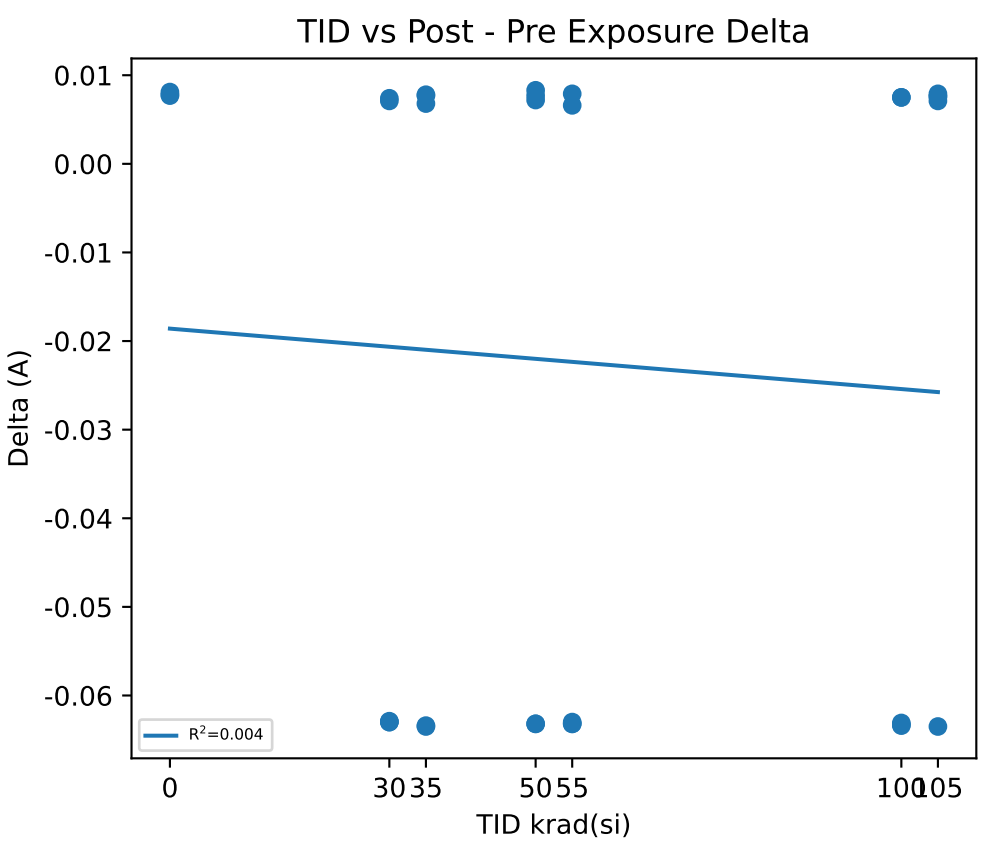
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7076	5.6457	-0.0619
2	0	CU2	5.6364	5.6465	0.0101
3	0	CU3	5.4957	5.5046	0.0089
11	30	Unbiased-30krad	5.6367	5.5752	-0.0615
12	30	Unbiased-30krad	5.5663	5.5038	-0.0625
13	30	Unbiased-30krad	5.6364	5.6461	0.0097
14	30	Unbiased-30krad	5.5665	5.5046	-0.0619
15	30	Unbiased-30krad	5.4956	5.5047	0.0091
16	35	Biased-30krad	5.4958	5.5046	0.0088
17	35	Biased-30krad	5.496	5.5049	0.0089
18	35	Biased-30krad	5.4962	5.5035	0.0073
19	35	Biased-30krad	5.5663	5.5753	0.009
20	35	Biased-30krad	5.6368	5.5752	-0.0616
30	50	Unbiased-50krad	5.6367	5.5753	-0.0614
31	50	Unbiased-50krad	5.6367	5.5752	-0.0615
32	50	Unbiased-50krad	5.5662	5.5043	-0.0619
33	50	Unbiased-50krad	5.6364	5.6463	0.0099
34	50	Unbiased-50krad	5.5661	5.5752	0.0091
40	55	Biased-50krad	5.7076	5.6463	-0.0613
41	55	Biased-50krad	5.6368	5.5752	-0.0616
42	55	Biased-50krad	5.7075	5.6463	-0.0612
43	55	Biased-50krad	5.8499	5.7886	-0.0613
44	55	Biased-50krad	5.637	5.6464	0.0094
45	100	Unbiased-100krad	5.637	5.575	-0.062
46	100	Unbiased-100krad	5.5662	5.575	0.0088
47	100	Unbiased-100krad	5.6367	5.5043	-0.1324
48	100	Unbiased-100krad	5.4962	5.5041	0.0079
49	100	Unbiased-100krad	5.5666	5.4337	-0.1329
50	105	Biased-100krad	5.5665	5.5042	-0.0623
51	105	Biased-100krad	5.7081	5.7176	0.0095
52	105	Biased-100krad	5.5665	5.5752	0.0087
53	105	Biased-100krad	5.6374	5.5752	-0.0622
54	105	Biased-100krad	5.5663	5.5045	-0.0618

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4957	5.6132	5.7076	0.10783	5.5046	5.5989	5.6465	0.081696	-0.0619	-0.0143	0.0101	0.041227
30	5.4956	5.5803	5.6367	0.058925	5.5038	5.5469	5.6461	0.063382	-0.0625	-0.03342	0.0097	0.039091
35	5.4958	5.5382	5.6368	0.062957	5.5035	5.5327	5.5753	0.038846	-0.0616	-0.00552	0.009	0.031357
50	5.5661	5.6084	5.6367	0.038587	5.5043	5.5753	5.6463	0.050205	-0.0619	-0.03316	0.0099	0.038945
55	5.6368	5.7078	5.8499	0.086957	5.5752	5.6606	5.7886	0.077923	-0.0616	-0.0472	0.0094	0.031641
100	5.4962	5.5805	5.637	0.058853	5.4337	5.5184	5.575	0.059128	-0.1329	-0.06212	0.0088	0.070501
105	5.5663	5.609	5.7081	0.06337	5.5042	5.5753	5.7176	0.087059	-0.0623	-0.03362	0.0095	0.038999

Device Test: 26.4 _ILIM_HS|HS_Sourcing/SW3/3/3///90.9/634//1.8///@HIGH_SIDE_OC





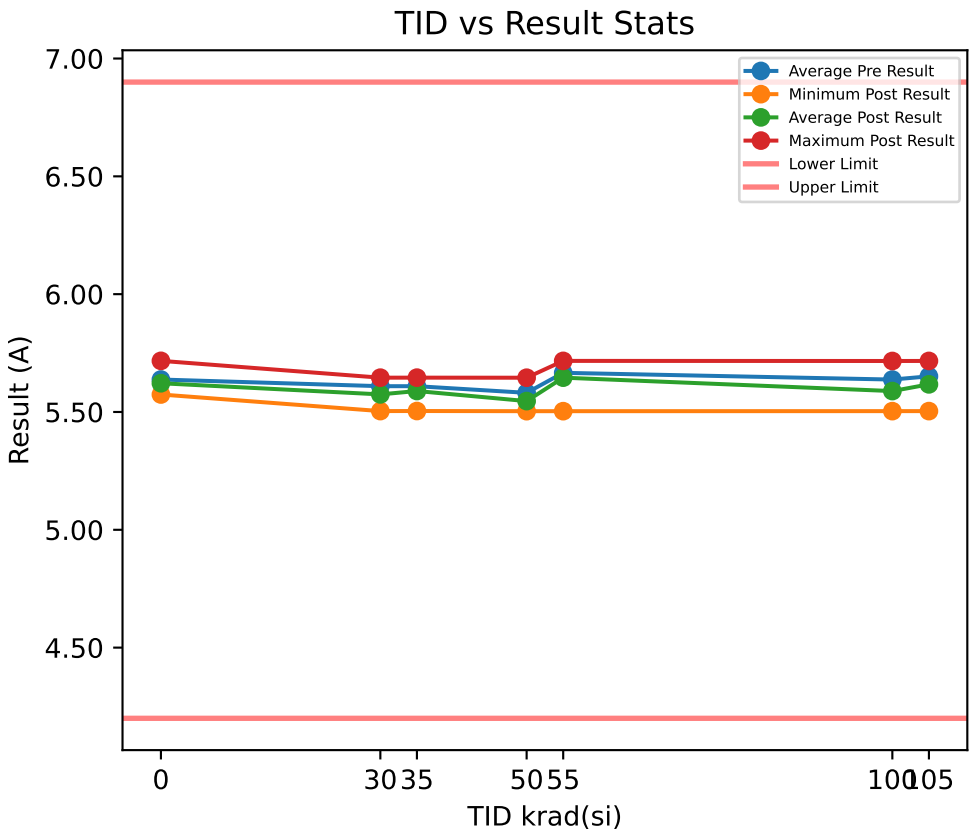
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

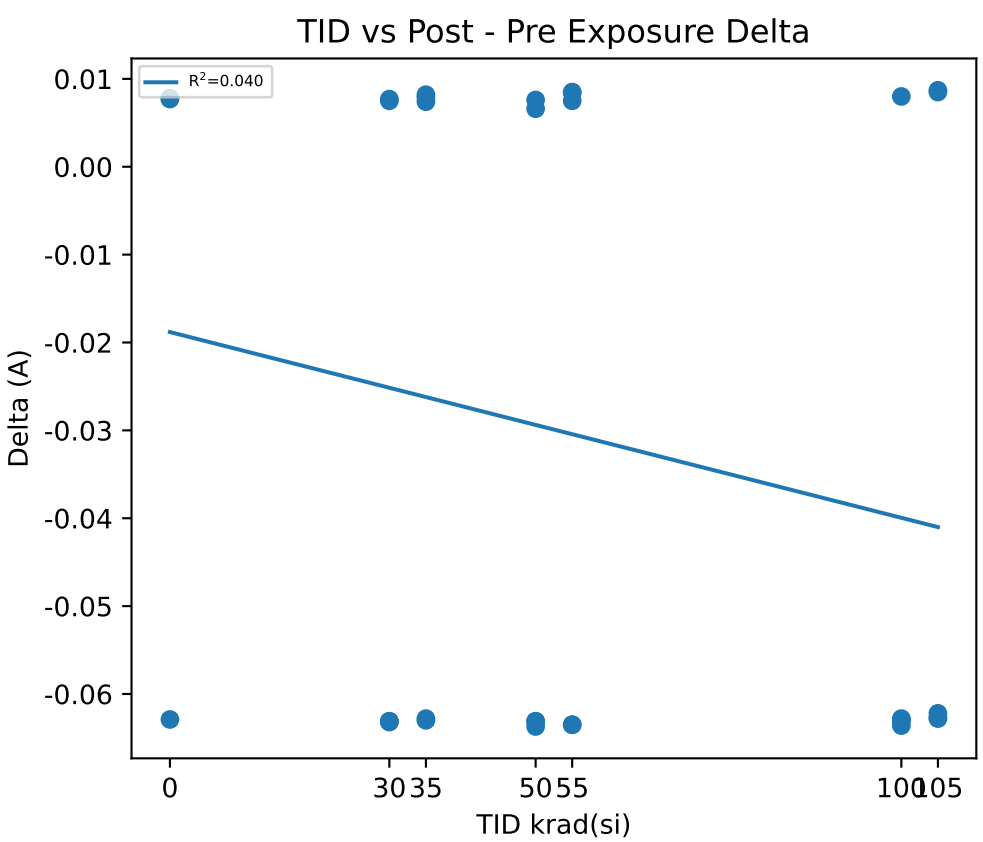
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7082	5.7163	0.0081
2	0	CU2	5.6375	5.6452	0.0077
3	0	CU3	5.5665	5.5743	0.0078
11	30	Unbiased-30krad	5.5663	5.5033	-0.063
12	30	Unbiased-30krad	5.4964	5.4335	-0.0629
13	30	Unbiased-30krad	5.6373	5.5743	-0.063
14	30	Unbiased-30krad	5.4962	5.5033	0.0071
15	30	Unbiased-30krad	5.4962	5.5036	0.0074
16	35	Biased-30krad	5.6376	5.6454	0.0078
17	35	Biased-30krad	5.6376	5.6453	0.0077
18	35	Biased-30krad	5.4966	5.5034	0.0068
19	35	Biased-30krad	5.7087	5.6452	-0.0635
20	35	Biased-30krad	5.6373	5.5739	-0.0634
30	50	Unbiased-50krad	5.4964	5.4332	-0.0632
31	50	Unbiased-50krad	5.6373	5.6456	0.0083
32	50	Unbiased-50krad	5.5664	5.5032	-0.0632
33	50	Unbiased-50krad	5.6375	5.6452	0.0077
34	50	Unbiased-50krad	5.4964	5.5036	0.0072
40	55	Biased-50krad	5.6373	5.5743	-0.063
41	55	Biased-50krad	5.4966	5.5032	0.0066
42	55	Biased-50krad	5.7085	5.6453	-0.0632
43	55	Biased-50krad	5.7796	5.7164	-0.0632
44	55	Biased-50krad	5.7084	5.7163	0.0079
45	100	Unbiased-100krad	5.6375	5.5742	-0.0633
46	100	Unbiased-100krad	5.5665	5.5034	-0.0631
47	100	Unbiased-100krad	5.5667	5.5742	0.0075
48	100	Unbiased-100krad	5.5664	5.5739	0.0075
49	100	Unbiased-100krad	5.4964	5.433	-0.0634
50	105	Biased-100krad	5.4965	5.433	-0.0635
51	105	Biased-100krad	5.6375	5.6454	0.0079
52	105	Biased-100krad	5.5667	5.5743	0.0076
53	105	Biased-100krad	5.6376	5.6452	0.0076
54	105	Biased-100krad	5.4962	5.5033	0.0071

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5665	5.6374	5.7082	0.07085	5.5743	5.6453	5.7163	0.071	0.0077	0.0078667	0.0081	0.00020817
30	5.4962	5.5385	5.6373	0.063018	5.4335	5.5036	5.5743	0.049781	-0.063	-0.03488	0.0074	0.038459
35	5.4966	5.6236	5.7087	0.07738	5.5034	5.6026	5.6454	0.06351	-0.0635	-0.02092	0.0078	0.038826
50	5.4964	5.5668	5.6375	0.0705	5.4332	5.5462	5.6456	0.095019	-0.0632	-0.02064	0.0083	0.038854
55	5.4966	5.6661	5.7796	0.10727	5.5032	5.6311	5.7164	0.09263	-0.0632	-0.03498	0.0079	0.038553
100	5.4964	5.5667	5.6375	0.049887	5.433	5.5317	5.5742	0.063119	-0.0634	-0.03496	0.0075	0.038761
105	5.4962	5.5669	5.6376	0.0706	5.433	5.5602	5.6454	0.092331	-0.0635	-0.00666	0.0079	0.031776

Device Test: 26.5 _ILIM_HS|HS_Sourcing/SW4/3/3///90.9/634//1.8///@HIGH_SIDE_OC





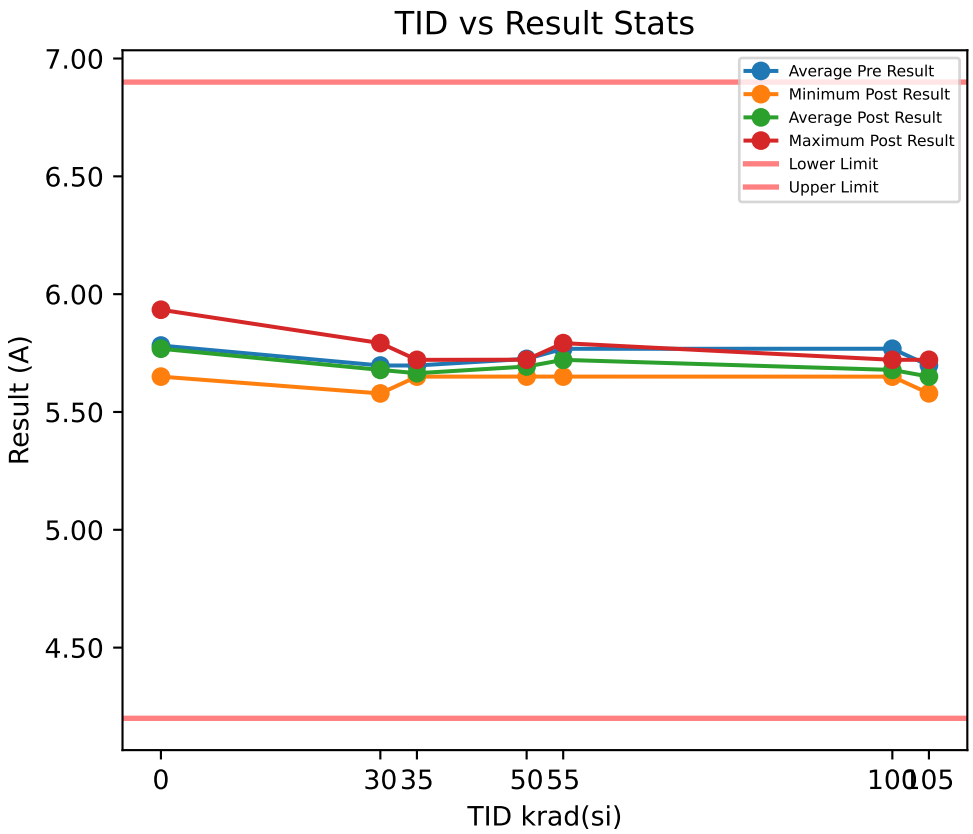
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

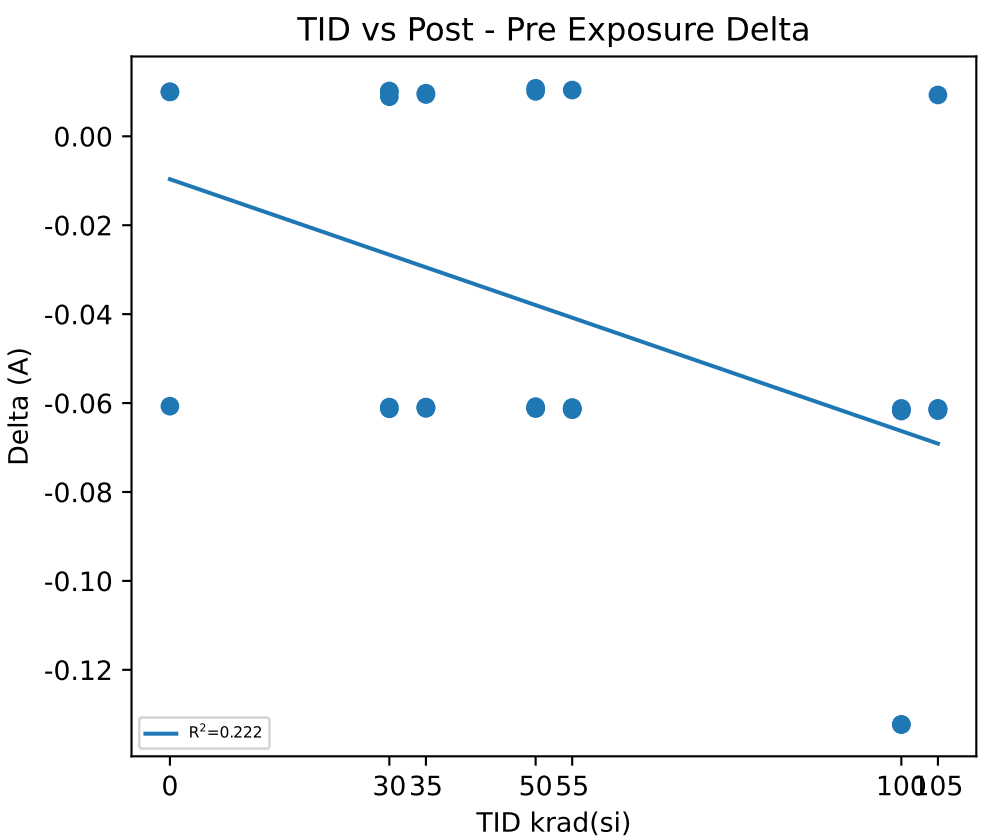
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7799	5.717	-0.0629
2	0	CU2	5.5665	5.5742	0.0077
3	0	CU3	5.5668	5.5746	0.0078
11	30	Unbiased-30krad	5.7088	5.6456	-0.0632
12	30	Unbiased-30krad	5.5669	5.5746	0.0077
13	30	Unbiased-30krad	5.6377	5.5746	-0.0631
14	30	Unbiased-30krad	5.5669	5.5038	-0.0631
15	30	Unbiased-30krad	5.5671	5.5746	0.0075
16	35	Biased-30krad	5.5664	5.5746	0.0082
17	35	Biased-30krad	5.5667	5.5746	0.0079
18	35	Biased-30krad	5.5671	5.5041	-0.063
19	35	Biased-30krad	5.6383	5.6457	0.0074
20	35	Biased-30krad	5.7085	5.6457	-0.0628
30	50	Unbiased-50krad	5.5667	5.5036	-0.0631
31	50	Unbiased-50krad	5.7091	5.6454	-0.0637
32	50	Unbiased-50krad	5.5672	5.5748	0.0076
33	50	Unbiased-50krad	5.5667	5.5036	-0.0631
34	50	Unbiased-50krad	5.4968	5.5034	0.0066
40	55	Biased-50krad	5.6372	5.6456	0.0084
41	55	Biased-50krad	5.5669	5.5034	-0.0635
42	55	Biased-50krad	5.7083	5.7168	0.0085
43	55	Biased-50krad	5.7803	5.7168	-0.0635
44	55	Biased-50krad	5.6381	5.6456	0.0075
45	100	Unbiased-100krad	5.7092	5.6456	-0.0636
46	100	Unbiased-100krad	5.6372	5.5744	-0.0628
47	100	Unbiased-100krad	5.7084	5.7164	0.008
48	100	Unbiased-100krad	5.5665	5.5036	-0.0629
49	100	Unbiased-100krad	5.5667	5.5036	-0.0631
50	105	Biased-100krad	5.5659	5.5037	-0.0622
51	105	Biased-100krad	5.7083	5.6456	-0.0627
52	105	Biased-100krad	5.6372	5.5744	-0.0628
53	105	Biased-100krad	5.7079	5.7166	0.0087
54	105	Biased-100krad	5.6373	5.6458	0.0085

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5665	5.6377	5.7799	0.12312	5.5742	5.6219	5.717	0.08233	-0.0629	-0.0158	0.0078	0.04079
30	5.5669	5.6095	5.7088	0.063409	5.5038	5.5746	5.6456	0.050134	-0.0632	-0.03484	0.0077	0.038742
35	5.5664	5.6094	5.7085	0.063478	5.5041	5.5889	5.6457	0.059272	-0.063	-0.02046	0.0082	0.038743
50	5.4968	5.5813	5.7091	0.077618	5.5034	5.5462	5.6454	0.063482	-0.0637	-0.03514	0.0076	0.038562
55	5.5669	5.6662	5.7803	0.081059	5.5034	5.6456	5.7168	0.08712	-0.0635	-0.02052	0.0085	0.039237
100	5.5665	5.6376	5.7092	0.071101	5.5036	5.5887	5.7164	0.092511	-0.0636	-0.04888	0.008	0.031798
105	5.5659	5.6513	5.7083	0.059457	5.5037	5.6172	5.7166	0.080961	-0.0628	-0.0341	0.0087	0.03898

Device Test: 27.2 _ILIM_HS|HS_Sourcing/SW1/7/7///90.9/634//1.8///@HIGH_SIDE_OC





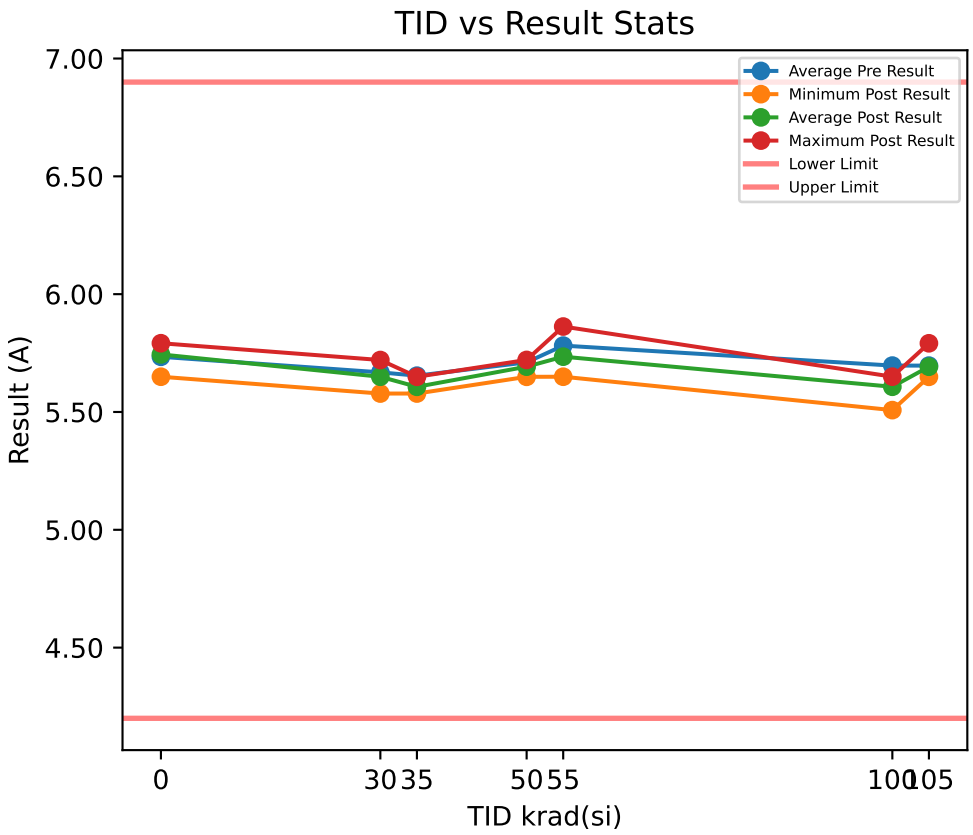
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

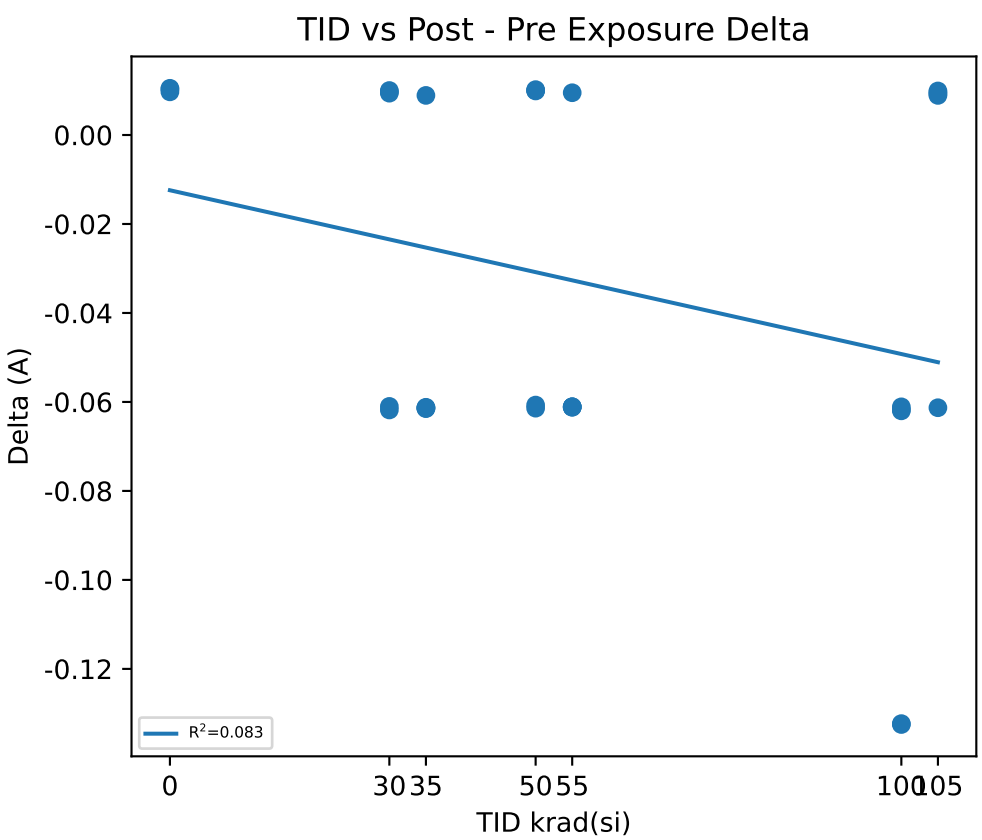
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9239	5.9339	0.01
2	0	CU2	5.6401	5.6501	0.01
3	0	CU3	5.782	5.7213	-0.0607
11	30	Unbiased-30krad	5.8533	5.7924	-0.0609
12	30	Unbiased-30krad	5.7113	5.7213	0.01
13	30	Unbiased-30krad	5.6403	5.6505	0.0102
14	30	Unbiased-30krad	5.7113	5.65	-0.0613
15	30	Unbiased-30krad	5.5698	5.5787	0.0089
16	35	Biased-30krad	5.7113	5.6501	-0.0612
17	35	Biased-30krad	5.7113	5.6504	-0.0609
18	35	Biased-30krad	5.6408	5.6502	0.0094
19	35	Biased-30krad	5.7115	5.7212	0.0097
20	35	Biased-30krad	5.7114	5.6504	-0.061
30	50	Unbiased-50krad	5.7111	5.7212	0.0101
31	50	Unbiased-50krad	5.7824	5.7212	-0.0612
32	50	Unbiased-50krad	5.711	5.6502	-0.0608
33	50	Unbiased-50krad	5.7114	5.6502	-0.0612
34	50	Unbiased-50krad	5.7111	5.7219	0.0108
40	55	Biased-50krad	5.7113	5.7217	0.0104
41	55	Biased-50krad	5.7824	5.7211	-0.0613
42	55	Biased-50krad	5.8532	5.7922	-0.061
43	55	Biased-50krad	5.7824	5.7209	-0.0615
44	55	Biased-50krad	5.7115	5.6502	-0.0613
45	100	Unbiased-100krad	5.7823	5.65	-0.1323
46	100	Unbiased-100krad	5.7117	5.6501	-0.0616
47	100	Unbiased-100krad	5.8536	5.7213	-0.1323
48	100	Unbiased-100krad	5.7114	5.6502	-0.0612
49	100	Unbiased-100krad	5.7827	5.7209	-0.0618
50	105	Biased-100krad	5.7117	5.65	-0.0617
51	105	Biased-100krad	5.7827	5.7215	-0.0612
52	105	Biased-100krad	5.6409	5.6502	0.0093
53	105	Biased-100krad	5.7115	5.6502	-0.0613
54	105	Biased-100krad	5.6406	5.5791	-0.0615

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6401	5.782	5.9239	0.1419	5.6501	5.7684	5.9339	0.14765	-0.0607	-0.013567	0.01	0.040819
30	5.5698	5.6972	5.8533	0.10516	5.5787	5.6786	5.7924	0.081181	-0.0613	-0.01862	0.0102	0.038782
35	5.6408	5.6973	5.7115	0.031562	5.6501	5.6645	5.7212	0.031719	-0.0612	-0.0328	0.0097	0.03866
50	5.711	5.7254	5.7824	0.031864	5.6502	5.6929	5.7219	0.039017	-0.0612	-0.03246	0.0108	0.039172
55	5.7113	5.7682	5.8532	0.059331	5.6502	5.7212	5.7922	0.050205	-0.0615	-0.04694	0.0104	0.032055
100	5.7114	5.7683	5.8536	0.059415	5.65	5.6785	5.7213	0.038889	-0.1323	-0.08984	-0.0612	0.038761
105	5.6406	5.6975	5.7827	0.059367	5.5791	5.6502	5.7215	0.050346	-0.0617	-0.04728	0.0093	0.03163

Device Test: 27.3 _ILIM_HS|HS_Sourcing/SW2/7/7///90.9/634//1.8///@HIGH_SIDE_OC





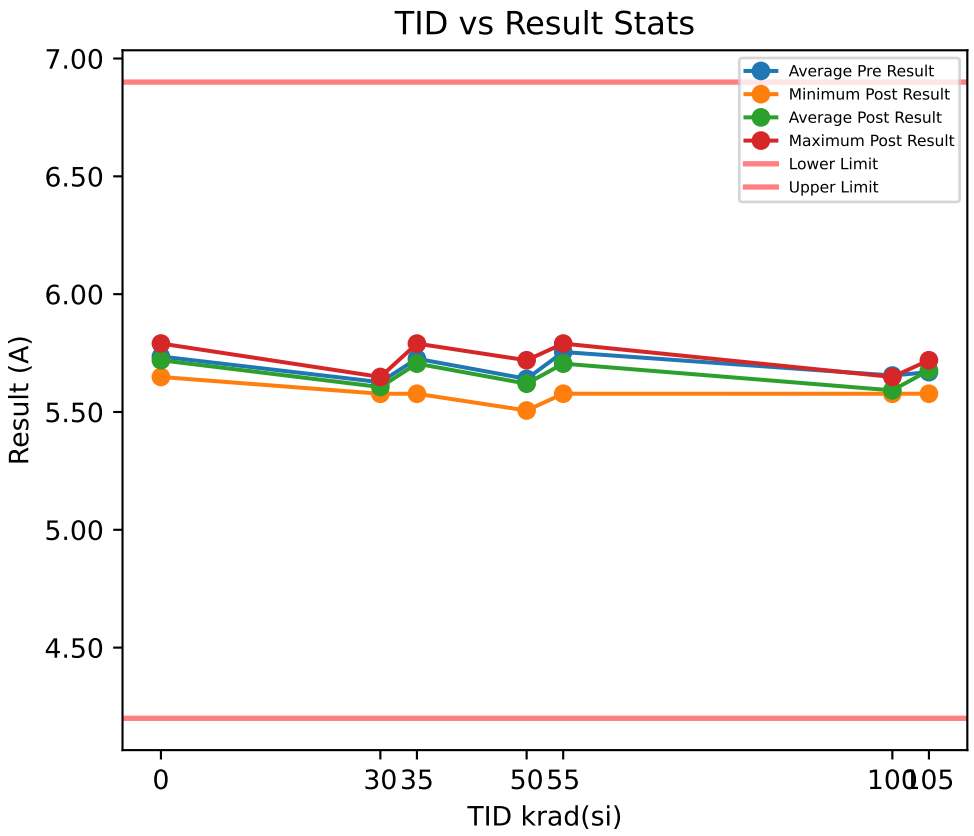
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

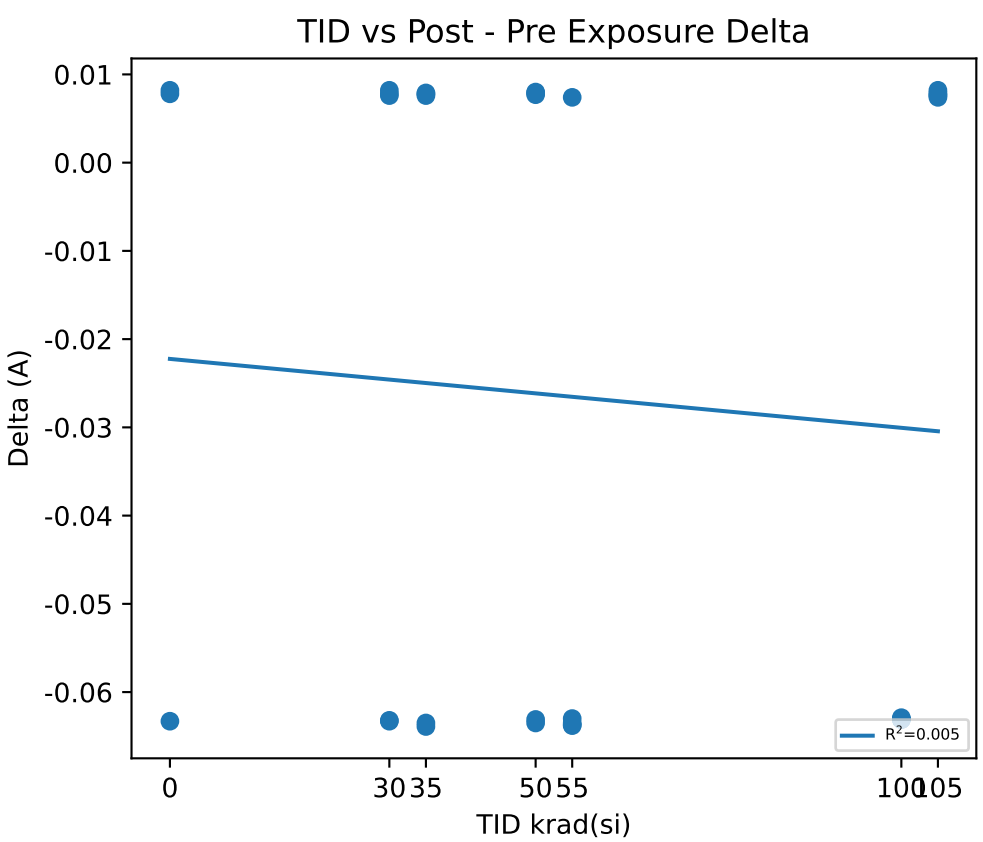
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7811	5.7916	0.0105
2	0	CU2	5.7815	5.7918	0.0103
3	0	CU3	5.6399	5.6496	0.0097
11	30	Unbiased-30krad	5.7105	5.7205	0.01
12	30	Unbiased-30krad	5.6399	5.6496	0.0097
13	30	Unbiased-30krad	5.7815	5.7205	-0.061
14	30	Unbiased-30krad	5.5692	5.5786	0.0094
15	30	Unbiased-30krad	5.64	5.5782	-0.0618
16	35	Biased-30krad	5.64	5.5786	-0.0614
17	35	Biased-30krad	5.64	5.5785	-0.0615
18	35	Biased-30krad	5.5694	5.5783	0.0089
19	35	Biased-30krad	5.7106	5.6493	-0.0613
20	35	Biased-30krad	5.7105	5.6493	-0.0612
30	50	Unbiased-50krad	5.7107	5.7207	0.01
31	50	Unbiased-50krad	5.7107	5.7209	0.0102
32	50	Unbiased-50krad	5.7105	5.6498	-0.0607
33	50	Unbiased-50krad	5.7106	5.7205	0.0099
34	50	Unbiased-50krad	5.7106	5.6492	-0.0614
40	55	Biased-50krad	5.7816	5.7204	-0.0612
41	55	Biased-50krad	5.7107	5.6496	-0.0611
42	55	Biased-50krad	5.7815	5.7204	-0.0611
43	55	Biased-50krad	5.9237	5.8626	-0.0611
44	55	Biased-50krad	5.7109	5.7204	0.0095
45	100	Unbiased-100krad	5.7819	5.6496	-0.1323
46	100	Unbiased-100krad	5.7111	5.6494	-0.0617
47	100	Unbiased-100krad	5.7109	5.6498	-0.0611
48	100	Unbiased-100krad	5.6403	5.5783	-0.062
49	100	Unbiased-100krad	5.6404	5.5079	-0.1325
50	105	Biased-100krad	5.6401	5.6493	0.0092
51	105	Biased-100krad	5.7816	5.7915	0.0099
52	105	Biased-100krad	5.6403	5.6492	0.0089
53	105	Biased-100krad	5.7818	5.7205	-0.0613
54	105	Biased-100krad	5.6401	5.6497	0.0096

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6399	5.7342	5.7815	0.081638	5.6496	5.7443	5.7918	0.082042	0.0097	0.010167	0.0105	0.00041633
30	5.5692	5.6682	5.7815	0.080659	5.5782	5.6495	5.7205	0.07105	-0.0618	-0.01874	0.01	0.038945
35	5.5694	5.6541	5.7106	0.059044	5.5783	5.6068	5.6493	0.038797	-0.0615	-0.0473	0.0089	0.031417
50	5.7105	5.7106	5.7107	8.3666e-05	5.6492	5.6922	5.7209	0.038999	-0.0614	-0.0184	0.0102	0.038935
55	5.7107	5.7817	5.9237	0.086916	5.6496	5.7347	5.8626	0.077804	-0.0612	-0.047	0.0095	0.031584
100	5.6403	5.6969	5.7819	0.0592	5.5079	5.607	5.6498	0.063421	-0.1325	-0.08992	-0.0611	0.03878
105	5.6401	5.6968	5.7818	0.077521	5.6492	5.692	5.7915	0.063555	-0.0613	-0.00474	0.0099	0.03162

Device Test: 27.4 _ILIM_HS|HS_Sourcing/SW3/7/7///90.9/634//1.8///@HIGH_SIDE_OC





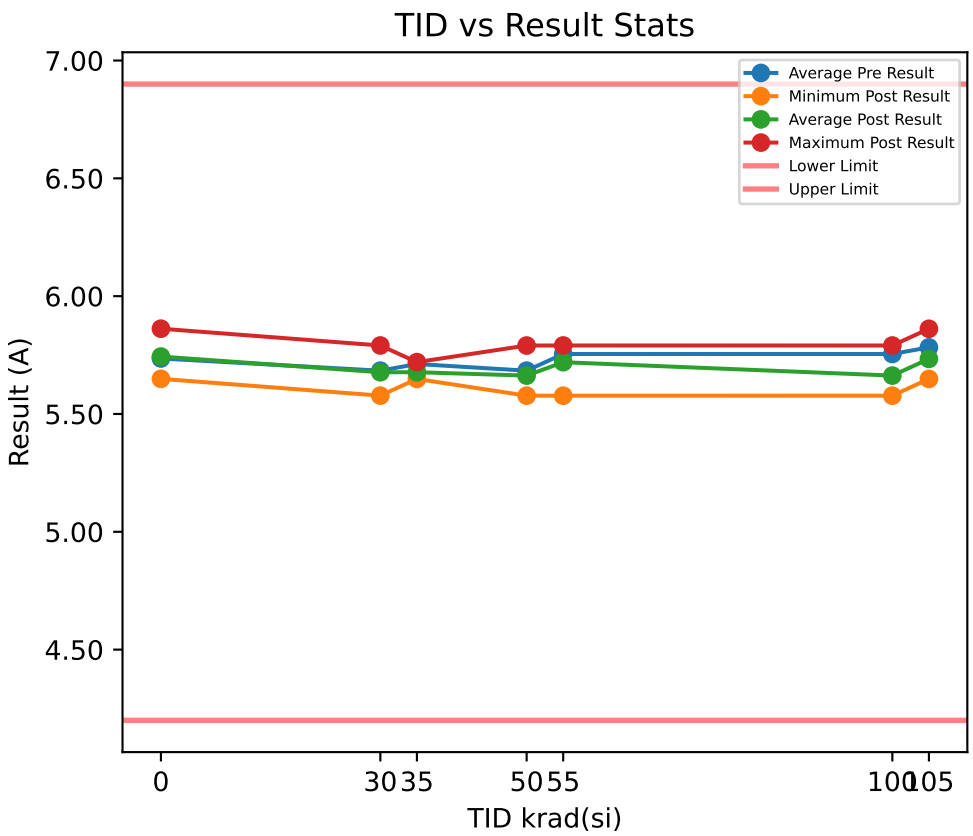
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

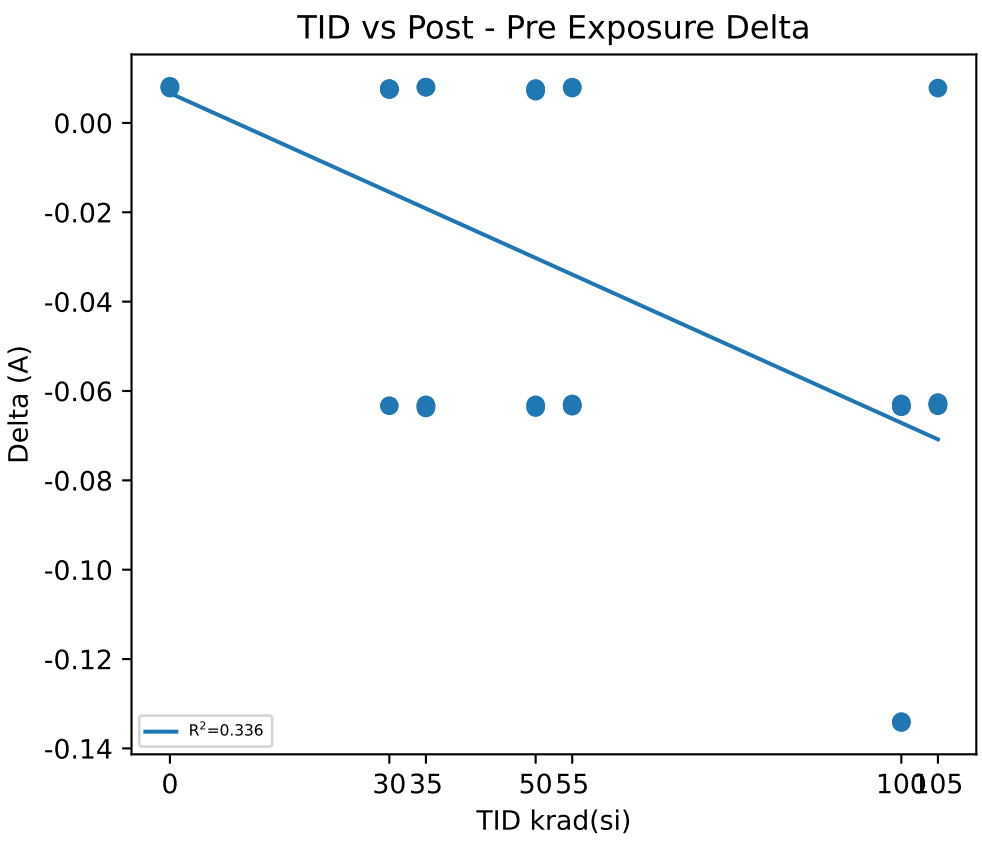
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8539	5.7906	-0.0633
2	0	CU2	5.7118	5.7196	0.0078
3	0	CU3	5.6404	5.6486	0.0082
11	30	Unbiased-30krad	5.6404	5.6486	0.0082
12	30	Unbiased-30krad	5.5696	5.5772	0.0076
13	30	Unbiased-30krad	5.7117	5.6485	-0.0632
14	30	Unbiased-30krad	5.5694	5.5772	0.0078
15	30	Unbiased-30krad	5.6408	5.5775	-0.0633
16	35	Biased-30krad	5.7828	5.7193	-0.0635
17	35	Biased-30krad	5.7116	5.7195	0.0079
18	35	Biased-30krad	5.5697	5.5773	0.0076
19	35	Biased-30krad	5.8541	5.7902	-0.0639
20	35	Biased-30krad	5.7118	5.7196	0.0078
30	50	Unbiased-50krad	5.5698	5.5063	-0.0635
31	50	Unbiased-50krad	5.7118	5.7195	0.0077
32	50	Unbiased-50krad	5.6406	5.5775	-0.0631
33	50	Unbiased-50krad	5.7116	5.7195	0.0079
34	50	Unbiased-50krad	5.5693	5.5773	0.008
40	55	Biased-50krad	5.7121	5.6483	-0.0638
41	55	Biased-50krad	5.6405	5.5775	-0.063
42	55	Biased-50krad	5.783	5.7195	-0.0635
43	55	Biased-50krad	5.8539	5.7902	-0.0637
44	55	Biased-50krad	5.7829	5.7903	0.0074
45	100	Unbiased-100krad	5.7116	5.6485	-0.0631
46	100	Unbiased-100krad	5.6406	5.5775	-0.0631
47	100	Unbiased-100krad	5.6404	5.5773	-0.0631
48	100	Unbiased-100krad	5.6405	5.5776	-0.0629
49	100	Unbiased-100krad	5.6406	5.5775	-0.0631
50	105	Biased-100krad	5.5697	5.5776	0.0079
51	105	Biased-100krad	5.712	5.7196	0.0076
52	105	Biased-100krad	5.7118	5.7192	0.0074
53	105	Biased-100krad	5.7116	5.7193	0.0077
54	105	Biased-100krad	5.6404	5.6486	0.0082

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6404	5.7354	5.8539	0.10868	5.6486	5.7196	5.7906	0.071	-0.0633	-0.015767	0.0082	0.041166
30	5.5694	5.6264	5.7117	0.059487	5.5772	5.6058	5.6486	0.039025	-0.0633	-0.02058	0.0082	0.038953
35	5.5697	5.726	5.8541	0.10544	5.5773	5.7052	5.7902	0.077772	-0.0639	-0.02082	0.0079	0.039144
50	5.5693	5.6406	5.7118	0.071075	5.5063	5.62	5.7195	0.095339	-0.0635	-0.0206	0.008	0.03898
55	5.6405	5.7545	5.8539	0.081075	5.5775	5.7052	5.7903	0.092488	-0.0638	-0.04932	0.0074	0.031709
100	5.6404	5.6547	5.7116	0.031786	5.5773	5.5917	5.6485	0.031764	-0.0631	-0.06306	-0.0629	8.9443e-05
105	5.5697	5.6691	5.712	0.063589	5.5776	5.6769	5.7196	0.063387	0.0074	0.00776	0.0082	0.00030496

Device Test: 27.5 _ILIM_HS|HS_Sourcing/SW4/7/7///90.9/634//1.8///@HIGH_SIDE_OC





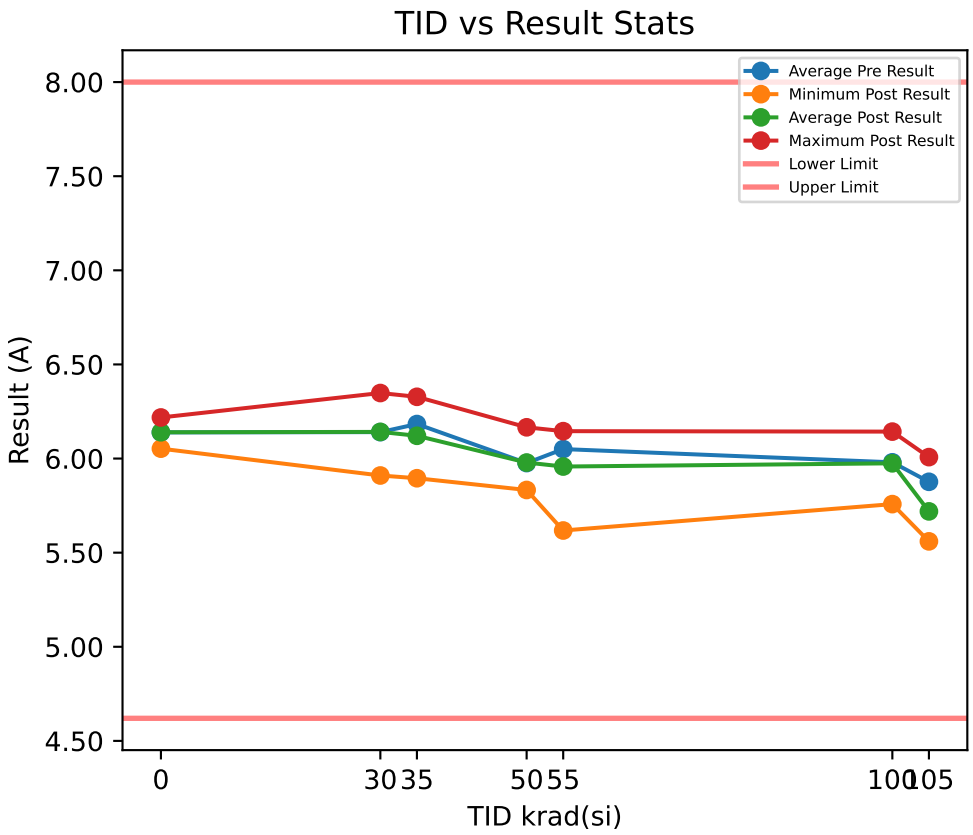
Test Results (Lower Limit = 4.2, Upper Limit = 6.9 (A))

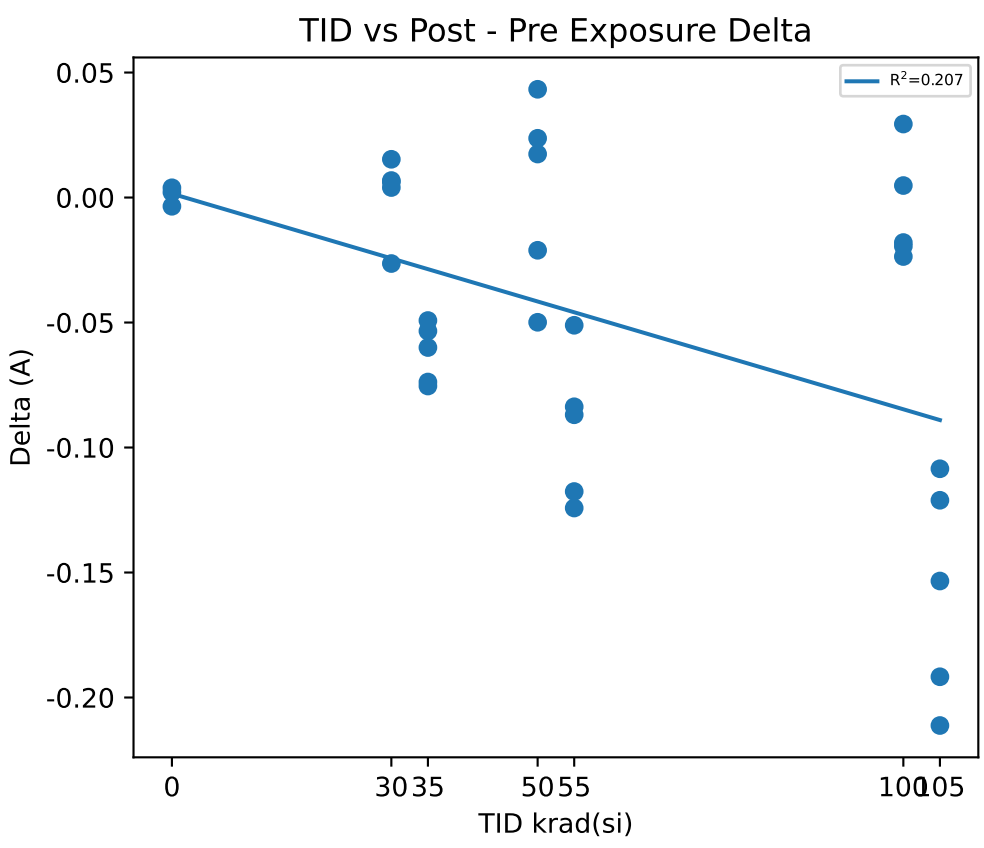
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8541	5.8619	0.0078
2	0	CU2	5.7118	5.7199	0.0081
3	0	CU3	5.6409	5.6491	0.0082
11	30	Unbiased-30krad	5.7832	5.7907	0.0075
12	30	Unbiased-30krad	5.7122	5.7197	0.0075
13	30	Unbiased-30krad	5.641	5.6487	0.0077
14	30	Unbiased-30krad	5.6412	5.5779	-0.0633
15	30	Unbiased-30krad	5.641	5.6486	0.0076
16	35	Biased-30krad	5.712	5.6486	-0.0634
17	35	Biased-30krad	5.6409	5.6489	0.008
18	35	Biased-30krad	5.641	5.649	0.008
19	35	Biased-30krad	5.7832	5.7201	-0.0631
20	35	Biased-30krad	5.7833	5.7195	-0.0638
30	50	Unbiased-50krad	5.6412	5.6486	0.0074
31	50	Unbiased-50krad	5.7834	5.7905	0.0071
32	50	Unbiased-50krad	5.712	5.7197	0.0077
33	50	Unbiased-50krad	5.641	5.5779	-0.0631
34	50	Unbiased-50krad	5.6414	5.5777	-0.0637
40	55	Biased-50krad	5.7117	5.7197	0.008
41	55	Biased-50krad	5.5698	5.5776	0.0078
42	55	Biased-50krad	5.8541	5.7907	-0.0634
43	55	Biased-50krad	5.8539	5.7906	-0.0633
44	55	Biased-50krad	5.7829	5.72	-0.0629
45	100	Unbiased-100krad	5.7832	5.7197	-0.0635
46	100	Unbiased-100krad	5.7827	5.6487	-0.134
47	100	Unbiased-100krad	5.8541	5.7906	-0.0635
48	100	Unbiased-100krad	5.6406	5.5777	-0.0629
49	100	Unbiased-100krad	5.7121	5.5779	-0.1342
50	105	Biased-100krad	5.7113	5.6487	-0.0626
51	105	Biased-100krad	5.8539	5.7906	-0.0633
52	105	Biased-100krad	5.7116	5.6487	-0.0629
53	105	Biased-100krad	5.8537	5.8615	0.0078
54	105	Biased-100krad	5.7827	5.7197	-0.063

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6409	5.7356	5.8541	0.10857	5.6491	5.7436	5.8619	0.10837	0.0078	0.0080333	0.0082	0.00020817
30	5.641	5.6837	5.7832	0.063571	5.5779	5.6771	5.7907	0.0809	-0.0633	-0.0066	0.0077	0.031696
35	5.6409	5.7121	5.7833	0.07115	5.6486	5.6772	5.7201	0.038871	-0.0638	-0.03486	0.008	0.039126
50	5.641	5.6838	5.7834	0.063561	5.5777	5.6629	5.7905	0.092462	-0.0637	-0.02092	0.0077	0.03878
55	5.5698	5.7545	5.8541	0.1189	5.5776	5.7197	5.7907	0.086977	-0.0634	-0.03476	0.008	0.038944
100	5.6406	5.7545	5.8541	0.081102	5.5777	5.6629	5.7906	0.092492	-0.1342	-0.09162	-0.0629	0.03878
105	5.7113	5.7826	5.8539	0.071175	5.6487	5.7338	5.8615	0.092488	-0.0633	-0.0488	0.0078	0.031641

Device Test: 28.2 _ILIM_LS|LS_Sourcing/SW1/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





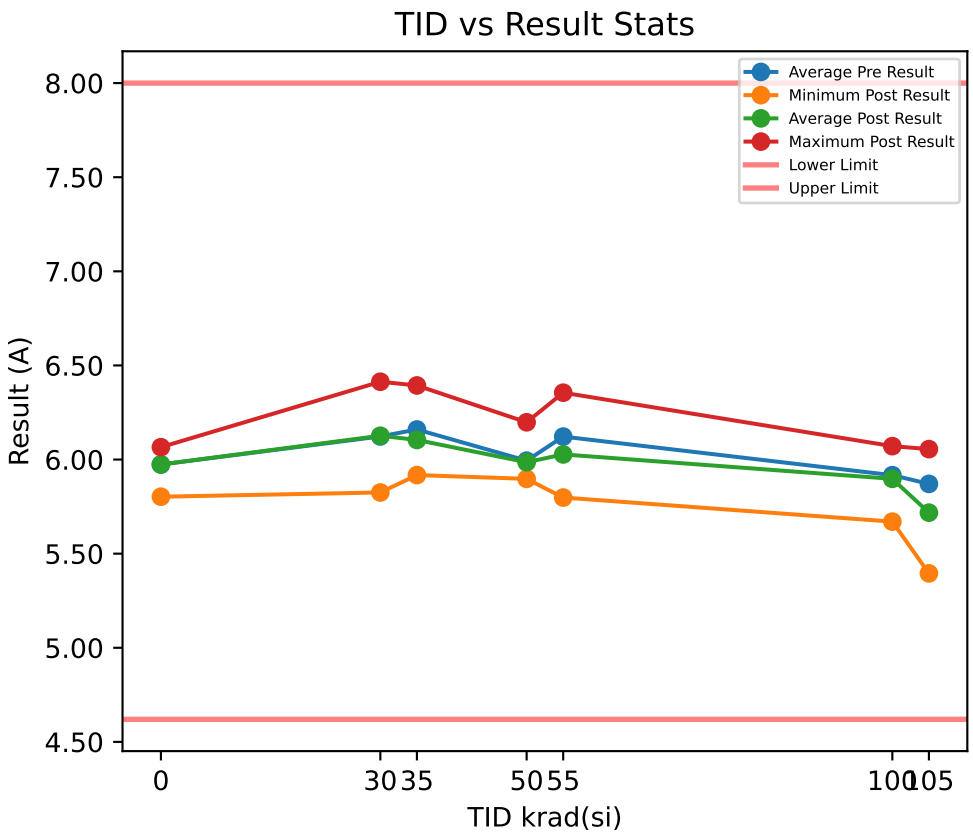
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

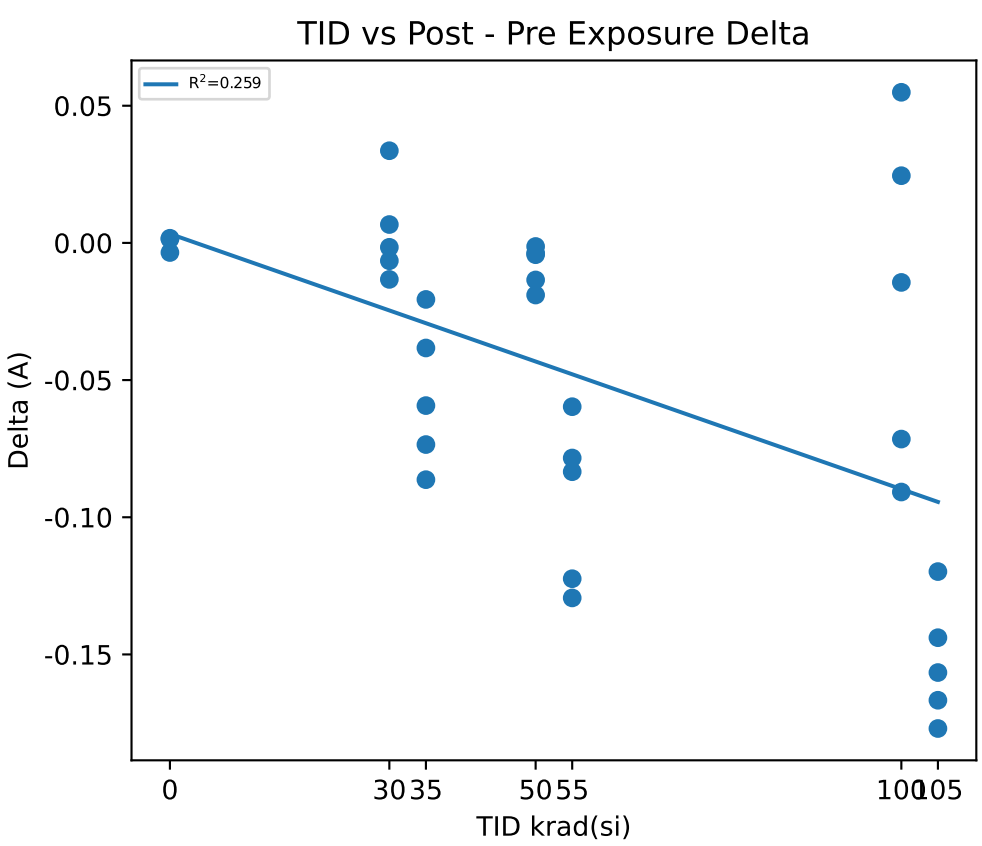
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0561	6.0526	-0.0035
2	0	CU2	6.2143	6.2182	0.0039
3	0	CU3	6.1461	6.1482	0.0021
11	30	Unbiased-30krad	6.109	6.1158	0.0068
12	30	Unbiased-30krad	6.2854	6.3007	0.0153
13	30	Unbiased-30krad	6.3441	6.3481	0.004
14	30	Unbiased-30krad	6.0597	6.0333	-0.0264
15	30	Unbiased-30krad	5.9038	5.91	0.0062
16	35	Biased-30krad	6.4018	6.328	-0.0738
17	35	Biased-30krad	6.0518	5.9764	-0.0754
18	35	Biased-30krad	6.182	6.1328	-0.0492
19	35	Biased-30krad	6.3319	6.2719	-0.06
20	35	Biased-30krad	5.9488	5.8954	-0.0534
30	50	Unbiased-50krad	5.8798	5.9231	0.0433
31	50	Unbiased-50krad	5.9614	5.9788	0.0174
32	50	Unbiased-50krad	5.8829	5.833	-0.0499
33	50	Unbiased-50krad	6.1871	6.166	-0.0211
34	50	Unbiased-50krad	5.9689	5.9926	0.0237
40	55	Biased-50krad	6.1847	6.0605	-0.1242
41	55	Biased-50krad	6.094	5.9764	-0.1176
42	55	Biased-50krad	6.0747	5.9878	-0.0869
43	55	Biased-50krad	5.7014	5.6177	-0.0837
44	55	Biased-50krad	6.1966	6.1455	-0.0511
45	100	Unbiased-100krad	6.1137	6.1431	0.0294
46	100	Unbiased-100krad	6.0289	6.0337	0.0048
47	100	Unbiased-100krad	5.7815	5.7579	-0.0236
48	100	Unbiased-100krad	6.0991	6.0811	-0.018
49	100	Unbiased-100krad	5.877	5.8575	-0.0195
50	105	Biased-100krad	6.1993	6.0076	-0.1917
51	105	Biased-100krad	5.744	5.6355	-0.1085
52	105	Biased-100krad	5.7712	5.56	-0.2112
53	105	Biased-100krad	5.7641	5.643	-0.1211
54	105	Biased-100krad	5.9038	5.7504	-0.1534

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0561	6.1388	6.2143	0.07935	6.0526	6.1397	6.2182	0.083129	-0.0035	0.00083333	0.0039	0.0038592
30	5.9038	6.1404	6.3441	0.17748	5.91	6.1416	6.3481	0.18302	-0.0264	0.00118	0.0153	0.016006
35	5.9488	6.1833	6.4018	0.18849	5.8954	6.1209	6.328	0.18545	-0.0754	-0.06236	-0.0492	0.011832
50	5.8798	5.976	6.1871	0.12525	5.833	5.9787	6.166	0.12206	-0.0499	0.00268	0.0433	0.037545
55	5.7014	6.0503	6.1966	0.2023	5.6177	5.9576	6.1455	0.20168	-0.1242	-0.0927	-0.0511	0.0294
100	5.7815	5.98	6.1137	0.14531	5.7579	5.9747	6.1431	0.16117	-0.0236	-0.00538	0.0294	0.022382
105	5.744	5.8765	6.1993	0.1912	5.56	5.7193	6.0076	0.17486	-0.2112	-0.15718	-0.1085	0.044146

Device Test: 28.3 _ILIM_LS|LS_Sourcing/SW2/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





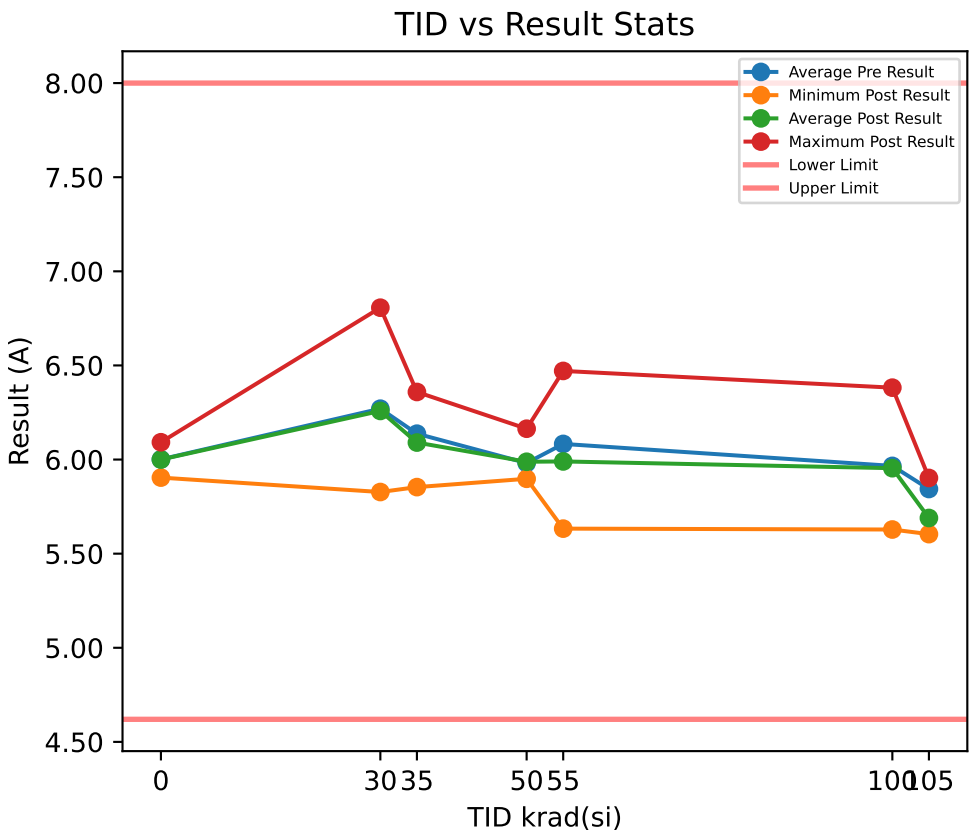
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

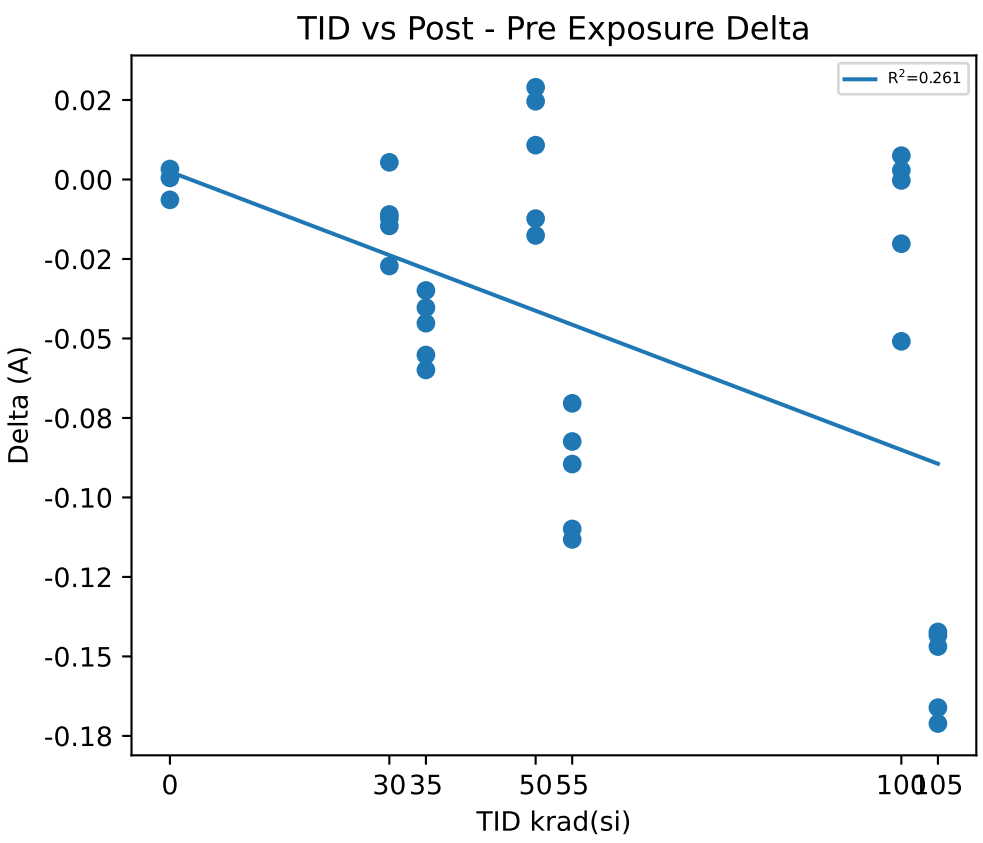
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.064	6.0657	0.0017
2	0	CU2	5.8012	5.8026	0.0014
3	0	CU3	6.0565	6.053	-0.0035
11	30	Unbiased-30krad	6.3047	6.3031	-0.0016
12	30	Unbiased-30krad	5.8316	5.8251	-0.0065
13	30	Unbiased-30krad	6.3797	6.4133	0.0336
14	30	Unbiased-30krad	6.1086	6.0953	-0.0133
15	30	Unbiased-30krad	5.989	5.9957	0.0067
16	35	Biased-30krad	6.3244	6.2861	-0.0383
17	35	Biased-30krad	5.9768	5.9175	-0.0593
18	35	Biased-30krad	6.0013	5.9807	-0.0206
19	35	Biased-30krad	6.0163	5.9428	-0.0735
20	35	Biased-30krad	6.4799	6.3936	-0.0863
30	50	Unbiased-50krad	5.9464	5.9329	-0.0135
31	50	Unbiased-50krad	5.9965	5.9922	-0.0043
32	50	Unbiased-50krad	5.9267	5.9077	-0.019
33	50	Unbiased-50krad	6.2017	6.198	-0.0037
34	50	Unbiased-50krad	5.8987	5.8974	-0.0013
40	55	Biased-50krad	5.9239	5.8405	-0.0834
41	55	Biased-50krad	6.3781	6.2557	-0.1224
42	55	Biased-50krad	6.4846	6.3552	-0.1294
43	55	Biased-50krad	5.9464	5.8867	-0.0597
44	55	Biased-50krad	5.8766	5.7982	-0.0784
45	100	Unbiased-100krad	5.8987	5.8843	-0.0144
46	100	Unbiased-100krad	5.9669	5.8761	-0.0908
47	100	Unbiased-100krad	5.7417	5.6702	-0.0715
48	100	Unbiased-100krad	6.0163	6.0712	0.0549
49	100	Unbiased-100krad	5.9614	5.9859	0.0245
50	105	Biased-100krad	6.1993	6.0554	-0.1439
51	105	Biased-100krad	5.6036	5.4838	-0.1198
52	105	Biased-100krad	5.5519	5.3953	-0.1566
53	105	Biased-100krad	5.9871	5.8101	-0.177
54	105	Biased-100krad	6.0115	5.8448	-0.1667

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8012	5.9739	6.064	0.14961	5.8026	5.9738	6.0657	0.14837	-0.0035	-0.00013333	0.0017	0.0029195
30	5.8316	6.1227	6.3797	0.22471	5.8251	6.1265	6.4133	0.23578	-0.0133	0.00378	0.0336	0.018194
35	5.9768	6.1597	6.4799	0.22845	5.9175	6.1041	6.3936	0.21966	-0.0863	-0.0556	-0.0206	0.026462
50	5.8987	5.994	6.2017	0.12147	5.8974	5.9856	6.198	0.12428	-0.019	-0.00836	-0.0013	0.0075444
55	5.8766	6.1219	6.4846	0.28608	5.7982	6.0273	6.3552	0.25828	-0.1294	-0.09466	-0.0597	0.029957
100	5.7417	5.917	6.0163	0.10652	5.6702	5.8975	6.0712	0.15024	-0.0908	-0.01946	0.0549	0.061816
105	5.5519	5.8707	6.1993	0.28032	5.3953	5.7179	6.0554	0.27266	-0.177	-0.1528	-0.1198	0.022144

Device Test: 28.4 _ILIM_LS|LS_Sourcing/SW3/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





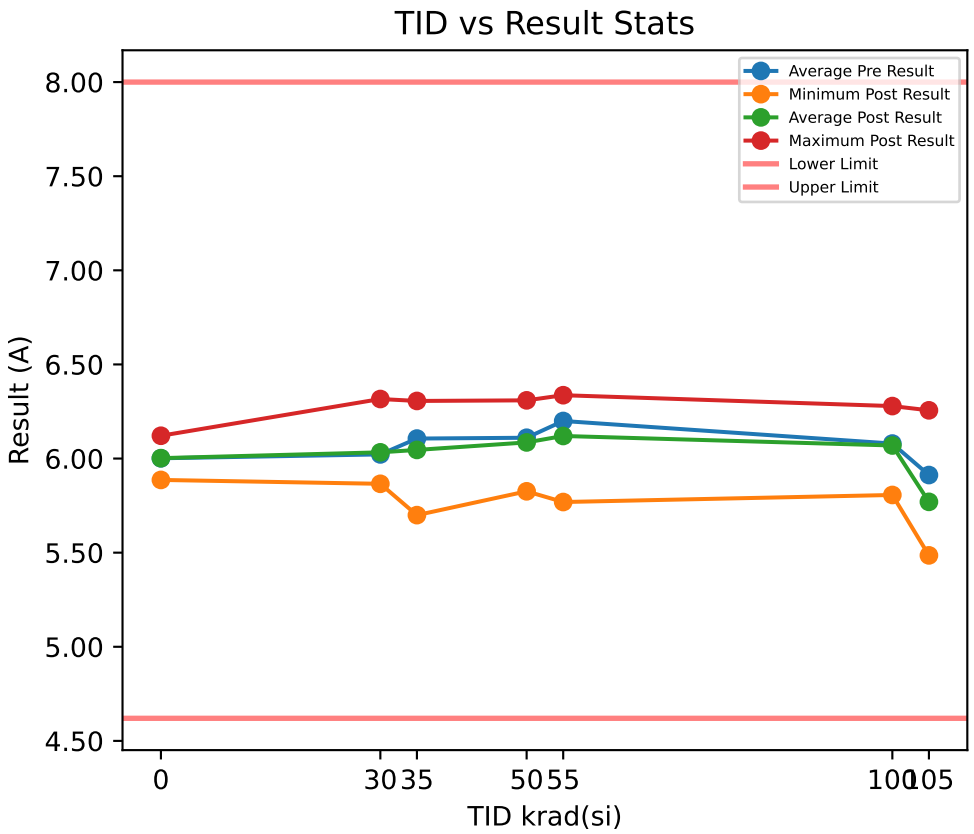
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

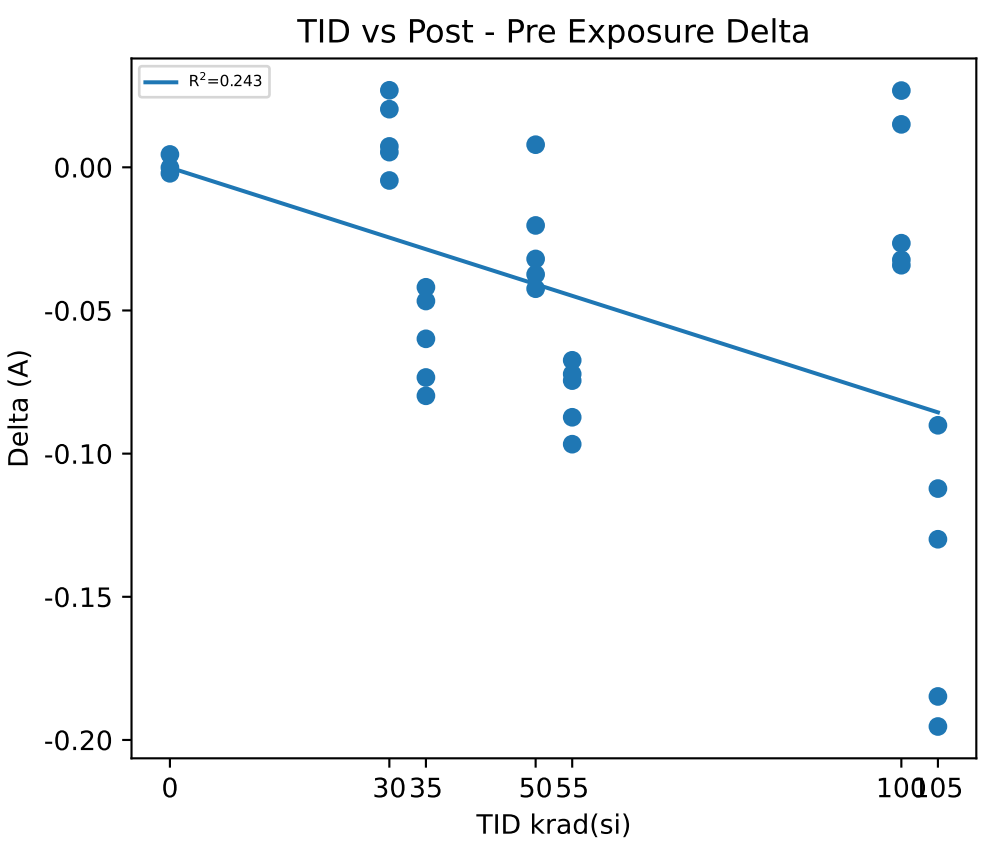
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9036	5.9041	0.0005
2	0	CU2	6.0008	6.0041	0.0033
3	0	CU3	6.0983	6.0919	-0.0064
11	30	Unbiased-30krad	6.3538	6.3416	-0.0122
12	30	Unbiased-30krad	6.8213	6.8067	-0.0146
13	30	Unbiased-30krad	6.2961	6.2689	-0.0272
14	30	Unbiased-30krad	6.041	6.0464	0.0054
15	30	Unbiased-30krad	5.8385	5.8275	-0.011
16	35	Biased-30krad	6.0264	5.9812	-0.0452
17	35	Biased-30krad	6.0864	6.0515	-0.0349
18	35	Biased-30krad	6.2464	6.2061	-0.0403
19	35	Biased-30krad	6.4142	6.359	-0.0552
20	35	Biased-30krad	5.9135	5.8536	-0.0599
30	50	Unbiased-50krad	5.9317	5.9563	0.0246
31	50	Unbiased-50krad	5.8732	5.9022	0.029
32	50	Unbiased-50krad	5.887	5.8978	0.0108
33	50	Unbiased-50krad	6.0387	6.0211	-0.0176
34	50	Unbiased-50krad	6.1761	6.1638	-0.0123
40	55	Biased-50krad	6.2361	6.1262	-0.1099
41	55	Biased-50krad	5.9581	5.8686	-0.0895
42	55	Biased-50krad	6.584	6.4708	-0.1132
43	55	Biased-50krad	5.7034	5.633	-0.0704
44	55	Biased-50krad	5.9336	5.8512	-0.0824
45	100	Unbiased-100krad	5.6734	5.6809	0.0075
46	100	Unbiased-100krad	5.6485	5.6283	-0.0202
47	100	Unbiased-100krad	5.8436	5.8433	-0.0003
48	100	Unbiased-100krad	6.379	6.3819	0.0029
49	100	Unbiased-100krad	6.287	6.2361	-0.0509
50	105	Biased-100krad	5.8254	5.6785	-0.1469
51	105	Biased-100krad	5.7461	5.6038	-0.1423
52	105	Biased-100krad	5.7863	5.6429	-0.1434
53	105	Biased-100krad	5.7915	5.6204	-0.1711
54	105	Biased-100krad	6.0683	5.9022	-0.1661

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9036	6.0009	6.0983	0.09735	5.9041	6	6.0919	0.093966	-0.0064	-0.00086667	0.0033	0.0049923
30	5.8385	6.2701	6.8213	0.3709	5.8275	6.2582	6.8067	0.36684	-0.0272	-0.01192	0.0054	0.011636
35	5.9135	6.1374	6.4142	0.19593	5.8536	6.0903	6.359	0.19688	-0.0599	-0.0471	-0.0349	0.010346
50	5.8732	5.9813	6.1761	0.12677	5.8978	5.9882	6.1638	0.11012	-0.0176	0.0069	0.029	0.021129
55	5.7034	6.083	6.584	0.33781	5.633	5.99	6.4708	0.32061	-0.1132	-0.09308	-0.0704	0.018228
100	5.6485	5.9663	6.379	0.34461	5.6283	5.9541	6.3819	0.33749	-0.0509	-0.0122	0.0075	0.02408
105	5.7461	5.8435	6.0683	0.12877	5.6038	5.6896	5.9022	0.12212	-0.1711	-0.15396	-0.1423	0.013587

Device Test: 28.5 _ILIM_LS|LS_Sourcing/SW4/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





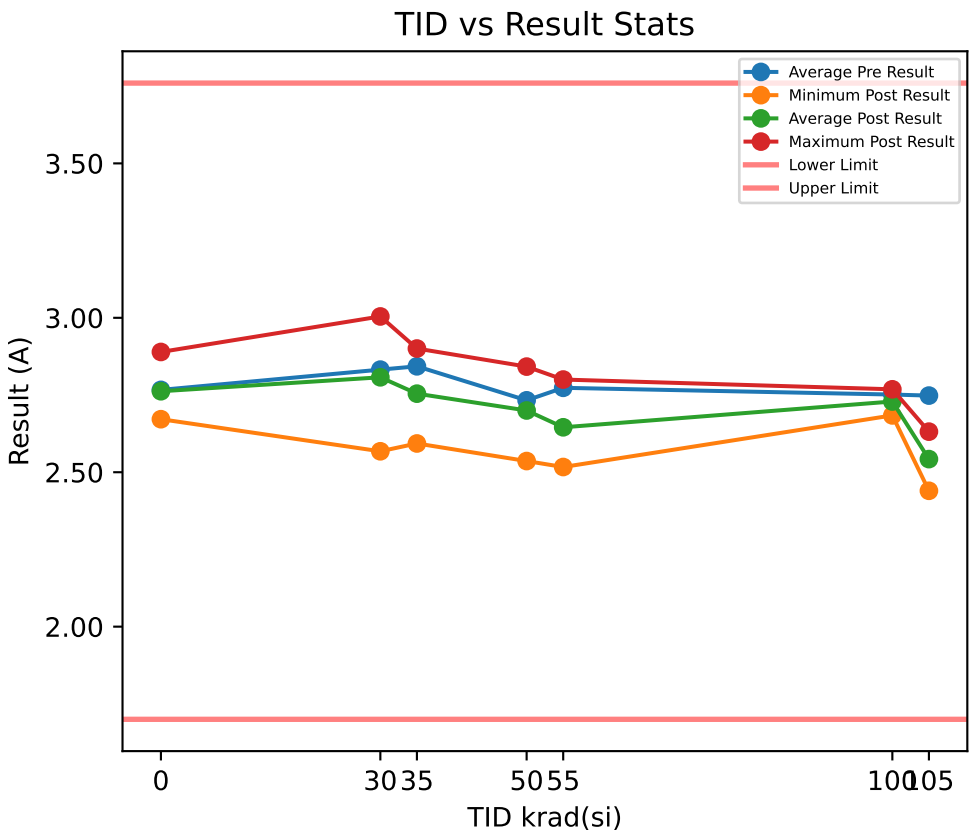
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

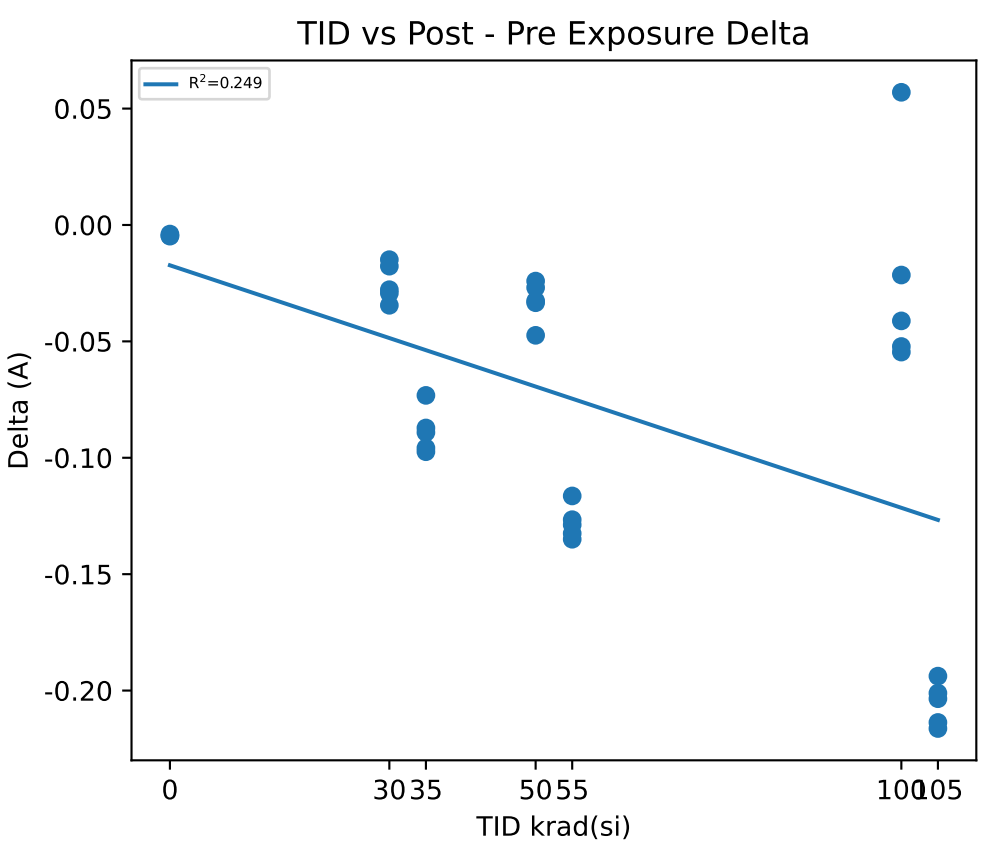
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0011	5.999	-0.0021
2	0	CU2	5.8819	5.8864	0.0045
3	0	CU3	6.1212	6.1211	-0.0001
11	30	Unbiased-30krad	5.951	5.9563	0.0053
12	30	Unbiased-30krad	6.0008	6.0081	0.0073
13	30	Unbiased-30krad	6.2894	6.3163	0.0269
14	30	Unbiased-30krad	5.8704	5.8658	-0.0046
15	30	Unbiased-30krad	5.9984	6.0187	0.0203
16	35	Biased-30krad	6.3794	6.306	-0.0734
17	35	Biased-30krad	6.2661	6.1863	-0.0798
18	35	Biased-30krad	6.2361	6.1942	-0.0419
19	35	Biased-30krad	5.9032	5.8433	-0.0599
20	35	Biased-30krad	5.7461	5.6994	-0.0467
30	50	Unbiased-50krad	6.3013	6.3092	0.0079
31	50	Unbiased-50krad	6.2187	6.1867	-0.032
32	50	Unbiased-50krad	6.0959	6.0756	-0.0203
33	50	Unbiased-50krad	6.0734	6.031	-0.0424
34	50	Unbiased-50krad	5.8633	5.8259	-0.0374
40	55	Biased-50krad	6.3238	6.2365	-0.0873
41	55	Biased-50krad	6.4087	6.3365	-0.0722
42	55	Biased-50krad	6.4015	6.3341	-0.0674
43	55	Biased-50krad	5.998	5.9235	-0.0745
44	55	Biased-50krad	5.8657	5.769	-0.0967
45	100	Unbiased-100krad	6.3111	6.2788	-0.0323
46	100	Unbiased-100krad	5.934	5.8998	-0.0342
47	100	Unbiased-100krad	5.7915	5.8065	0.015
48	100	Unbiased-100krad	6.2827	6.2562	-0.0265
49	100	Unbiased-100krad	6.0789	6.1057	0.0268
50	105	Biased-100krad	6.3684	6.2562	-0.1122
51	105	Biased-100krad	5.6734	5.5833	-0.0901
52	105	Biased-100krad	5.9005	5.7706	-0.1299
53	105	Biased-100krad	5.6809	5.4856	-0.1953
54	105	Biased-100krad	5.9388	5.754	-0.1848

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8819	6.0014	6.1212	0.11965	5.8864	6.0022	6.1211	0.11738	-0.0021	0.00076667	0.0045	0.0033843
30	5.8704	6.022	6.2894	0.15853	5.8658	6.033	6.3163	0.1695	-0.0046	0.01104	0.0269	0.012538
35	5.7461	6.1062	6.3794	0.26831	5.6994	6.0458	6.306	0.26003	-0.0798	-0.06034	-0.0419	0.016398
50	5.8633	6.1105	6.3013	0.16644	5.8259	6.0857	6.3092	0.18079	-0.0424	-0.02484	0.0079	0.020062
55	5.8657	6.1995	6.4087	0.25102	5.769	6.1199	6.3365	0.25889	-0.0967	-0.07962	-0.0674	0.012055
100	5.7915	6.0796	6.3111	0.22307	5.8065	6.0694	6.2788	0.21092	-0.0342	-0.01024	0.0268	0.028871
105	5.6734	5.9124	6.3684	0.28262	5.4856	5.7699	6.2562	0.29681	-0.1953	-0.14246	-0.0901	0.045825

Device Test: 28.6 _ILIM_LS|LS_Sinking/SW1/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK





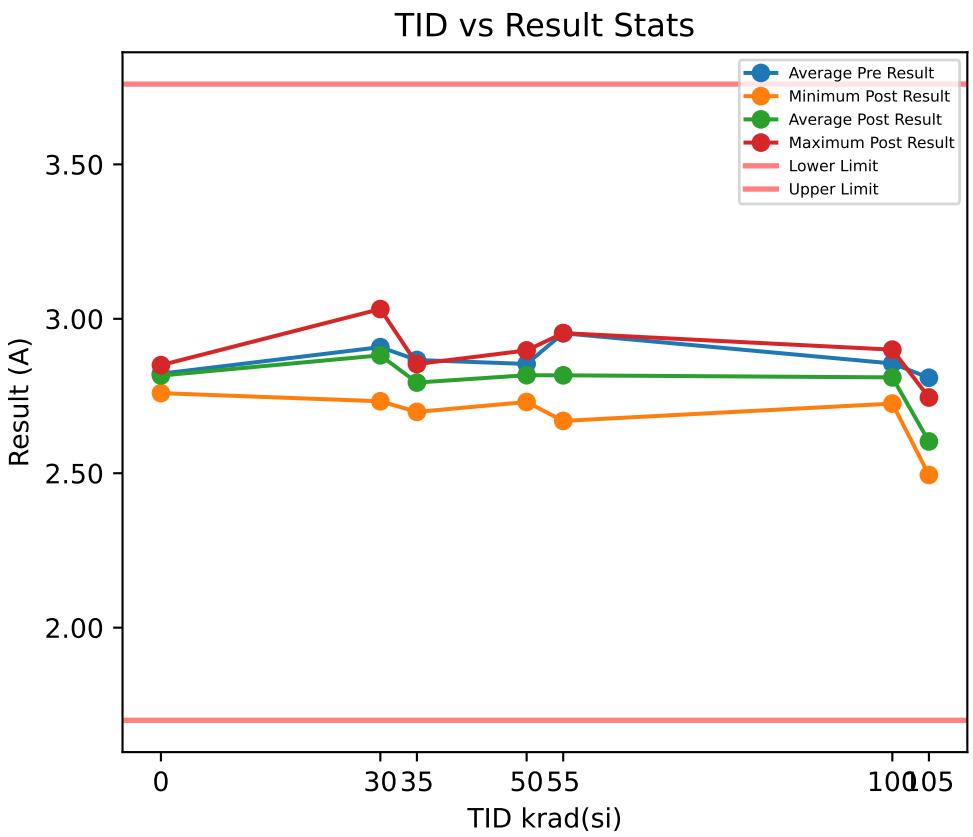
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

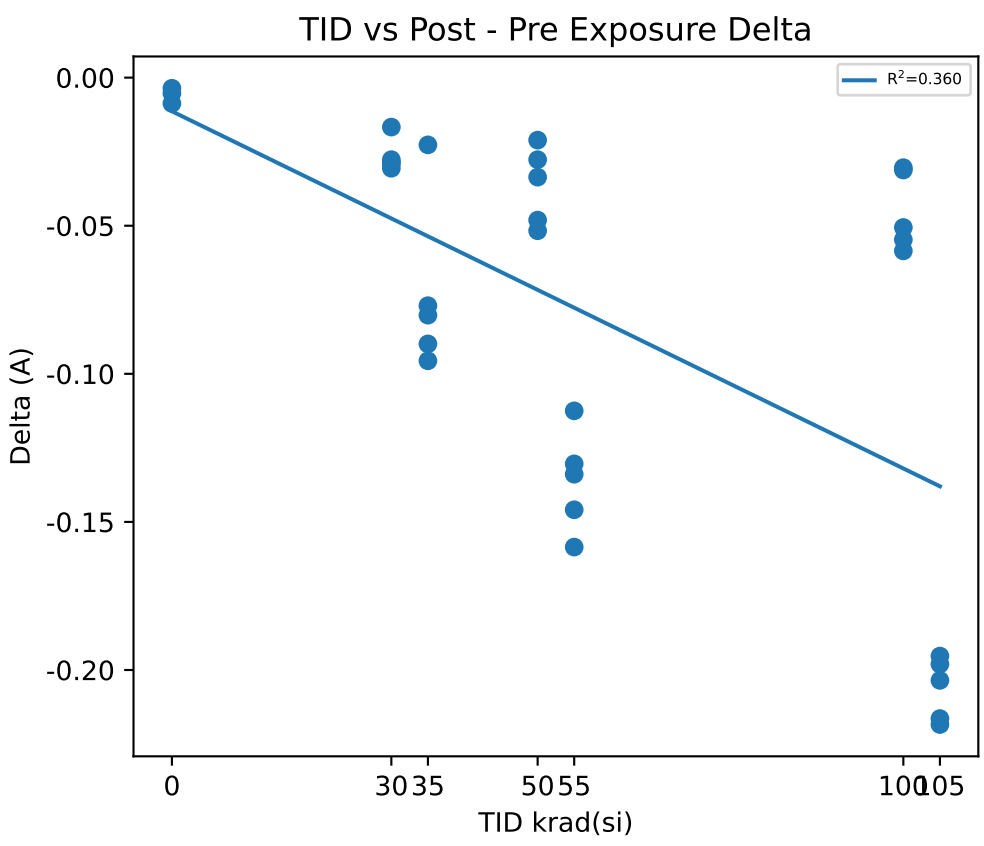
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.7303	2.7255	-0.0048
2	0	CU2	2.8933	2.8894	-0.0039
3	0	CU3	2.6763	2.6717	-0.0046
11	30	Unbiased-30krad	2.8097	2.7804	-0.0293
12	30	Unbiased-30krad	3.0389	3.0044	-0.0345
13	30	Unbiased-30krad	2.9489	2.934	-0.0149
14	30	Unbiased-30krad	2.7781	2.7503	-0.0278
15	30	Unbiased-30krad	2.5855	2.5678	-0.0177
16	35	Biased-30krad	2.9331	2.8357	-0.0974
17	35	Biased-30krad	2.6723	2.5991	-0.0732
18	35	Biased-30krad	2.9308	2.8436	-0.0872
19	35	Biased-30krad	2.9896	2.9005	-0.0891
20	35	Biased-30krad	2.6889	2.5931	-0.0958
30	50	Unbiased-50krad	2.7852	2.7583	-0.0269
31	50	Unbiased-50krad	2.7288	2.6954	-0.0334
32	50	Unbiased-50krad	2.5603	2.5362	-0.0241
33	50	Unbiased-50krad	2.8894	2.842	-0.0474
34	50	Unbiased-50krad	2.7004	2.6678	-0.0326
40	55	Biased-50krad	2.9351	2.8001	-0.135
41	55	Biased-50krad	2.7726	2.6401	-0.1325
42	55	Biased-50krad	2.8132	2.6844	-0.1288
43	55	Biased-50krad	2.6333	2.5169	-0.1164
44	55	Biased-50krad	2.7126	2.586	-0.1266
45	100	Unbiased-100krad	2.8097	2.7685	-0.0412
46	100	Unbiased-100krad	2.7801	2.7586	-0.0215
47	100	Unbiased-100krad	2.7556	2.701	-0.0546
48	100	Unbiased-100krad	2.7852	2.733	-0.0522
49	100	Unbiased-100krad	2.627	2.684	0.057
50	105	Biased-100krad	2.8349	2.6314	-0.2035
51	105	Biased-100krad	2.6337	2.4399	-0.1938
52	105	Biased-100krad	2.7008	2.4845	-0.2163
53	105	Biased-100krad	2.8037	2.59	-0.2137
54	105	Biased-100krad	2.7678	2.5667	-0.2011

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6763	2.7666	2.8933	0.11297	2.6717	2.7622	2.8894	0.1134	-0.0048	-0.0044333	-0.0039	0.00047258
30	2.5855	2.8322	3.0389	0.17366	2.5678	2.8074	3.0044	0.17047	-0.0345	-0.02484	-0.0149	0.0082425
35	2.6723	2.8429	2.9896	0.15017	2.5931	2.7544	2.9005	0.14667	-0.0974	-0.08854	-0.0732	0.0095999
50	2.5603	2.7328	2.8894	0.12051	2.5362	2.6999	2.842	0.11341	-0.0474	-0.03288	-0.0241	0.0090004
55	2.6333	2.7734	2.9351	0.11298	2.5169	2.6455	2.8001	0.10668	-0.135	-0.12786	-0.1164	0.0071818
100	2.627	2.7515	2.8097	0.072211	2.684	2.729	2.7685	0.036268	-0.0546	-0.0225	0.057	0.046323
105	2.6337	2.7482	2.8349	0.081145	2.4399	2.5425	2.6314	0.078479	-0.2163	-0.20568	-0.1938	0.0092732

Device Test: 28.7 _ILIM_LS|LS_Sinking/SW2/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK





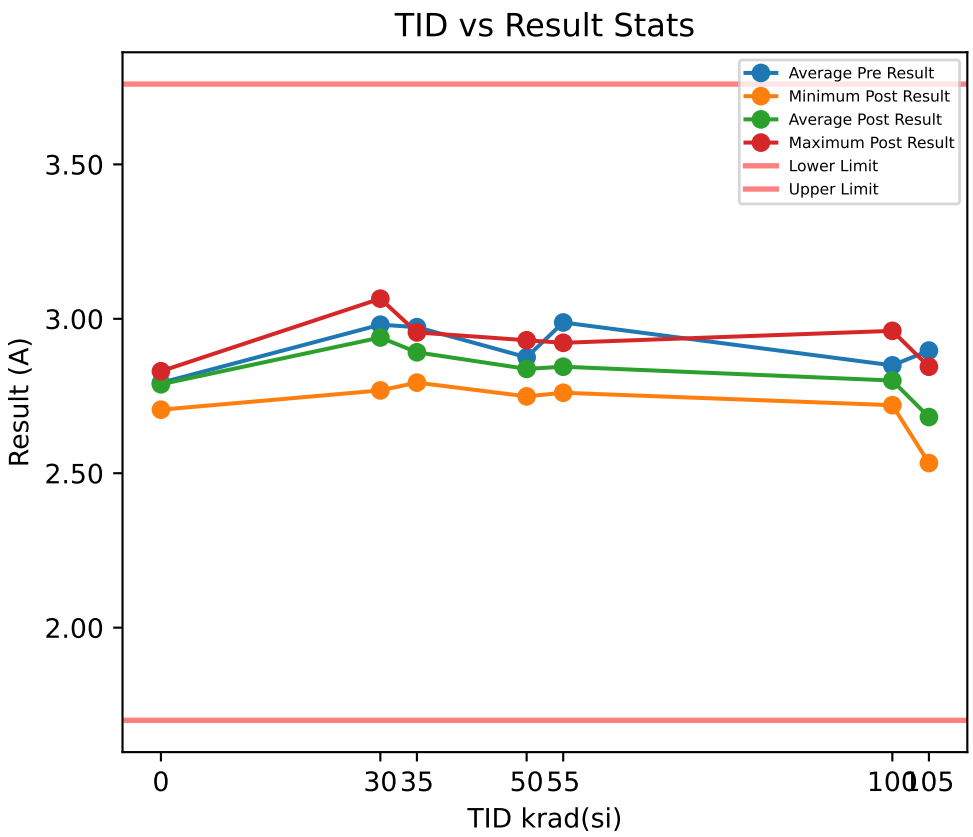
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

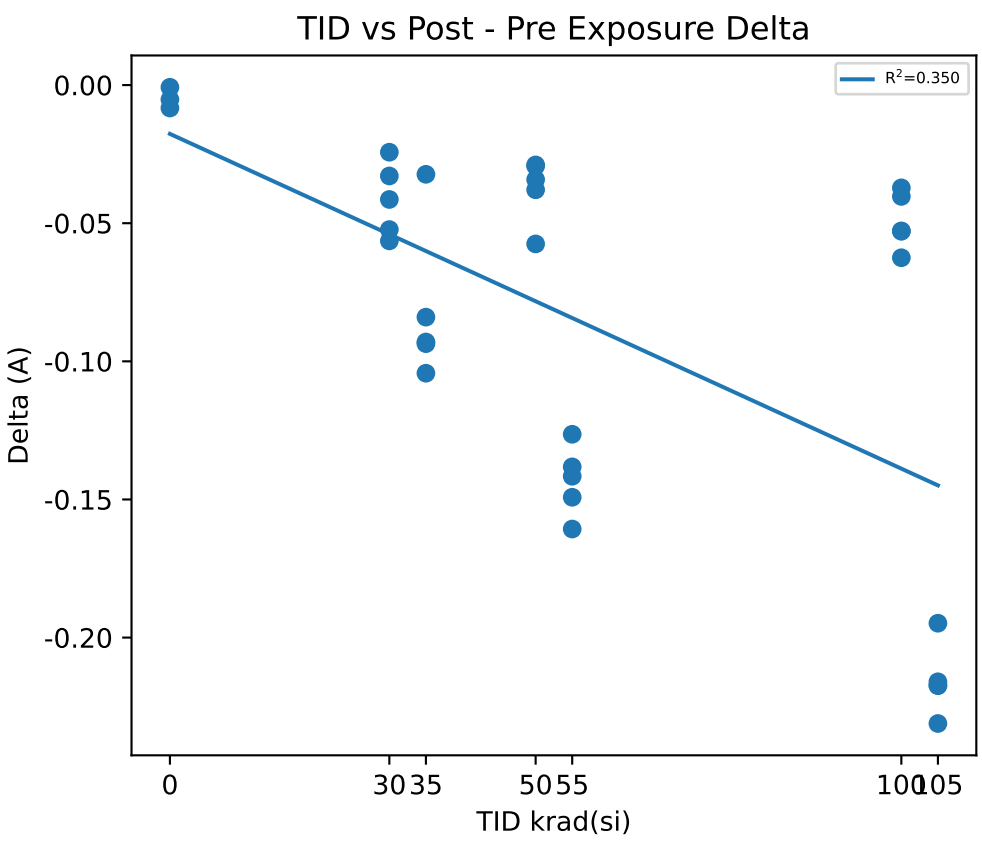
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.8432	2.8396	-0.0036
2	0	CU2	2.7647	2.7594	-0.0053
3	0	CU3	2.8586	2.8499	-0.0087
11	30	Unbiased-30krad	3.0054	2.9767	-0.0287
12	30	Unbiased-30krad	2.7595	2.7428	-0.0167
13	30	Unbiased-30krad	3.0606	3.0316	-0.029
14	30	Unbiased-30krad	2.9552	2.9246	-0.0306
15	30	Unbiased-30krad	2.7607	2.733	-0.0277
16	35	Biased-30krad	2.8803	2.8033	-0.077
17	35	Biased-30krad	2.8625	2.7823	-0.0802
18	35	Biased-30krad	2.7213	2.6986	-0.0227
19	35	Biased-30krad	2.9434	2.8535	-0.0899
20	35	Biased-30krad	2.9257	2.8301	-0.0956
30	50	Unbiased-50krad	2.7517	2.7306	-0.0211
31	50	Unbiased-50krad	2.8191	2.7914	-0.0277
32	50	Unbiased-50krad	2.8645	2.8128	-0.0517
33	50	Unbiased-50krad	2.9458	2.8977	-0.0481
34	50	Unbiased-50krad	2.8882	2.8546	-0.0336
40	55	Biased-50krad	2.8933	2.7808	-0.1125
41	55	Biased-50krad	3.0953	2.9494	-0.1459
42	55	Biased-50krad	3.1123	2.9538	-0.1585
43	55	Biased-50krad	2.8657	2.7318	-0.1339
44	55	Biased-50krad	2.7998	2.6694	-0.1304
45	100	Unbiased-100krad	2.8728	2.8424	-0.0304
46	100	Unbiased-100krad	2.7923	2.7417	-0.0506
47	100	Unbiased-100krad	2.784	2.7255	-0.0585
48	100	Unbiased-100krad	2.9548	2.9001	-0.0547
49	100	Unbiased-100krad	2.8732	2.842	-0.0312
50	105	Biased-100krad	2.9616	2.7452	-0.2164
51	105	Biased-100krad	2.7402	2.5422	-0.198
52	105	Biased-100krad	2.6897	2.4944	-0.1953
53	105	Biased-100krad	2.7445	2.541	-0.2035
54	105	Biased-100krad	2.9099	2.6915	-0.2184

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7647	2.8222	2.8586	0.05036	2.7594	2.8163	2.8499	0.049545	-0.0087	-0.0058667	-0.0036	0.0025968
30	2.7595	2.9083	3.0606	0.14031	2.733	2.8817	3.0316	0.13669	-0.0306	-0.02654	-0.0167	0.0055985
35	2.7213	2.8666	2.9434	0.087618	2.6986	2.7936	2.8535	0.059513	-0.0956	-0.07308	-0.0227	0.02913
50	2.7517	2.8539	2.9458	0.073127	2.7306	2.8174	2.8977	0.063371	-0.0517	-0.03644	-0.0211	0.013121
55	2.7998	2.9533	3.1123	0.14167	2.6694	2.817	2.9538	0.12903	-0.1585	-0.13624	-0.1125	0.017263
100	2.784	2.8554	2.9548	0.069963	2.7255	2.8103	2.9001	0.074156	-0.0585	-0.04508	-0.0304	0.013335
105	2.6897	2.8092	2.9616	0.11895	2.4944	2.6029	2.7452	0.10884	-0.2184	-0.20632	-0.1953	0.010561

Device Test: 28.8 _ILIM_LS|LS_Sinking/SW3/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK





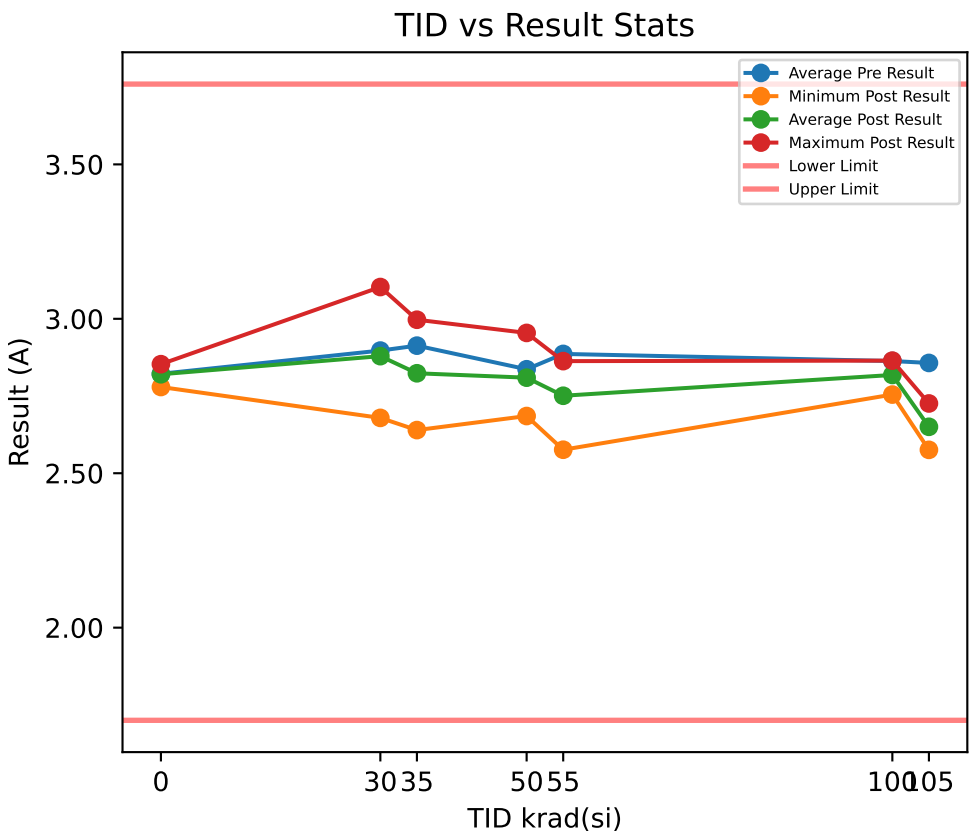
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

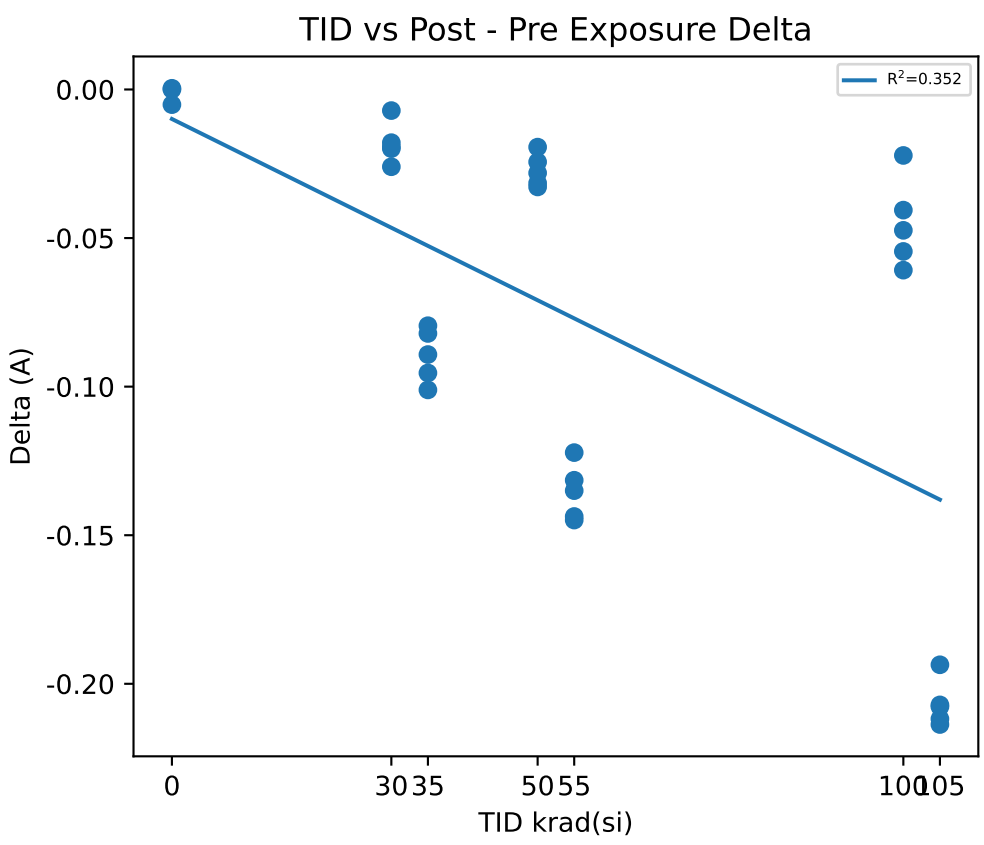
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.8365	2.8282	-0.0083
2	0	CU2	2.831	2.8302	-0.0008
3	0	CU3	2.7109	2.7057	-0.0052
11	30	Unbiased-30krad	3.0162	2.9598	-0.0564
12	30	Unbiased-30krad	2.9415	2.9001	-0.0414
13	30	Unbiased-30krad	3.0896	3.0653	-0.0243
14	30	Unbiased-30krad	3.0564	3.0041	-0.0523
15	30	Unbiased-30krad	2.801	2.7681	-0.0329
16	35	Biased-30krad	3.0489	2.9559	-0.093
17	35	Biased-30krad	2.968	2.8744	-0.0936
18	35	Biased-30krad	2.97	2.9377	-0.0323
19	35	Biased-30krad	2.9806	2.8966	-0.084
20	35	Biased-30krad	2.8977	2.7934	-0.1043
30	50	Unbiased-50krad	2.7777	2.7488	-0.0289
31	50	Unbiased-50krad	2.7974	2.7681	-0.0293
32	50	Unbiased-50krad	2.8649	2.827	-0.0379
33	50	Unbiased-50krad	2.9723	2.9148	-0.0575
34	50	Unbiased-50krad	2.9648	2.9306	-0.0342
40	55	Biased-50krad	3.0142	2.865	-0.1492
41	55	Biased-50krad	2.9822	2.844	-0.1382
42	55	Biased-50krad	3.0639	2.9223	-0.1416
43	55	Biased-50krad	2.887	2.7606	-0.1264
44	55	Biased-50krad	2.9933	2.8326	-0.1607
45	100	Unbiased-100krad	2.7828	2.7203	-0.0625
46	100	Unbiased-100krad	2.7694	2.7322	-0.0372
47	100	Unbiased-100krad	2.8195	2.7792	-0.0403
48	100	Unbiased-100krad	3.0138	2.961	-0.0528
49	100	Unbiased-100krad	2.861	2.8081	-0.0529
50	105	Biased-100krad	3.0608	2.8448	-0.216
51	105	Biased-100krad	2.8215	2.6267	-0.1948
52	105	Biased-100krad	2.7504	2.533	-0.2174
53	105	Biased-100krad	2.8855	2.6682	-0.2173
54	105	Biased-100krad	2.9676	2.7365	-0.2311

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7109	2.7928	2.8365	0.070981	2.7057	2.788	2.8302	0.07131	-0.0083	-0.0047667	-0.0008	0.0037687
30	2.801	2.9809	3.0896	0.11476	2.7681	2.9395	3.0653	0.11329	-0.0564	-0.04146	-0.0243	0.013308
35	2.8977	2.973	3.0489	0.053672	2.7934	2.8916	2.9559	0.063686	-0.1043	-0.08144	-0.0323	0.028396
50	2.7777	2.8754	2.9723	0.090997	2.7488	2.8379	2.9306	0.08282	-0.0575	-0.03756	-0.0289	0.01175
55	2.887	2.9881	3.0639	0.064633	2.7606	2.8449	2.9223	0.058424	-0.1607	-0.14322	-0.1264	0.012768
100	2.7694	2.8493	3.0138	0.098605	2.7203	2.8002	2.961	0.096654	-0.0625	-0.04914	-0.0372	0.010329
105	2.7504	2.8972	3.0608	0.12159	2.533	2.6818	2.8448	0.11718	-0.2311	-0.21532	-0.1948	0.013027

Device Test: 28.9 _ILIM_LS|LS_Sinking/SW4/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK





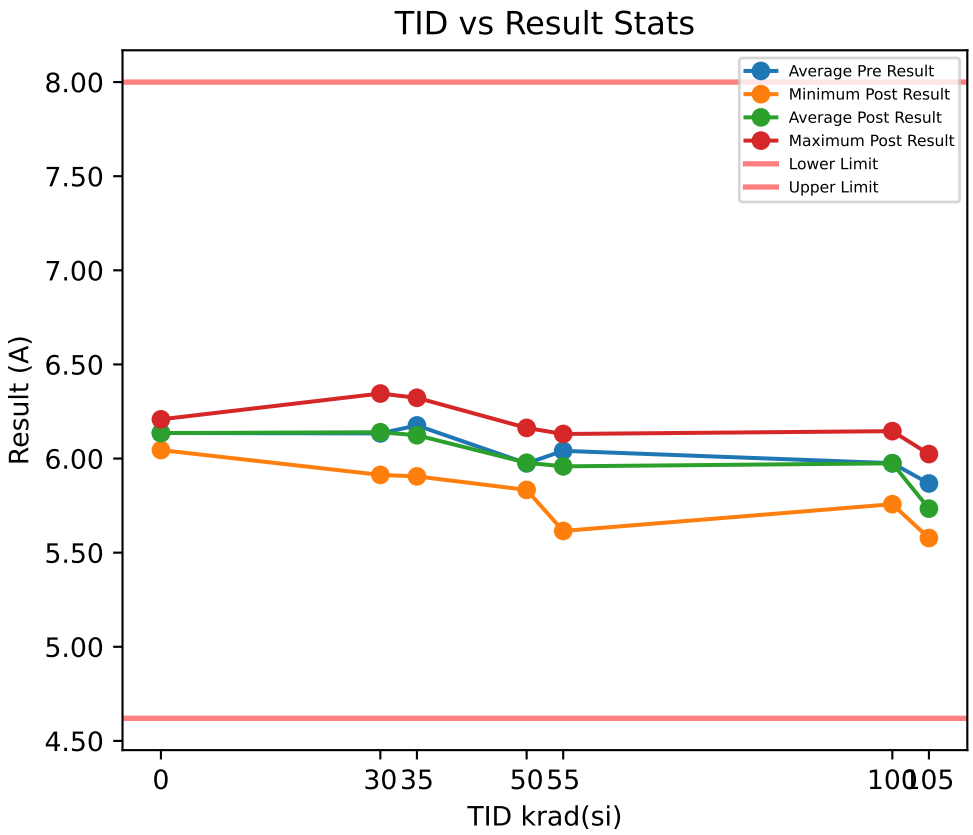
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

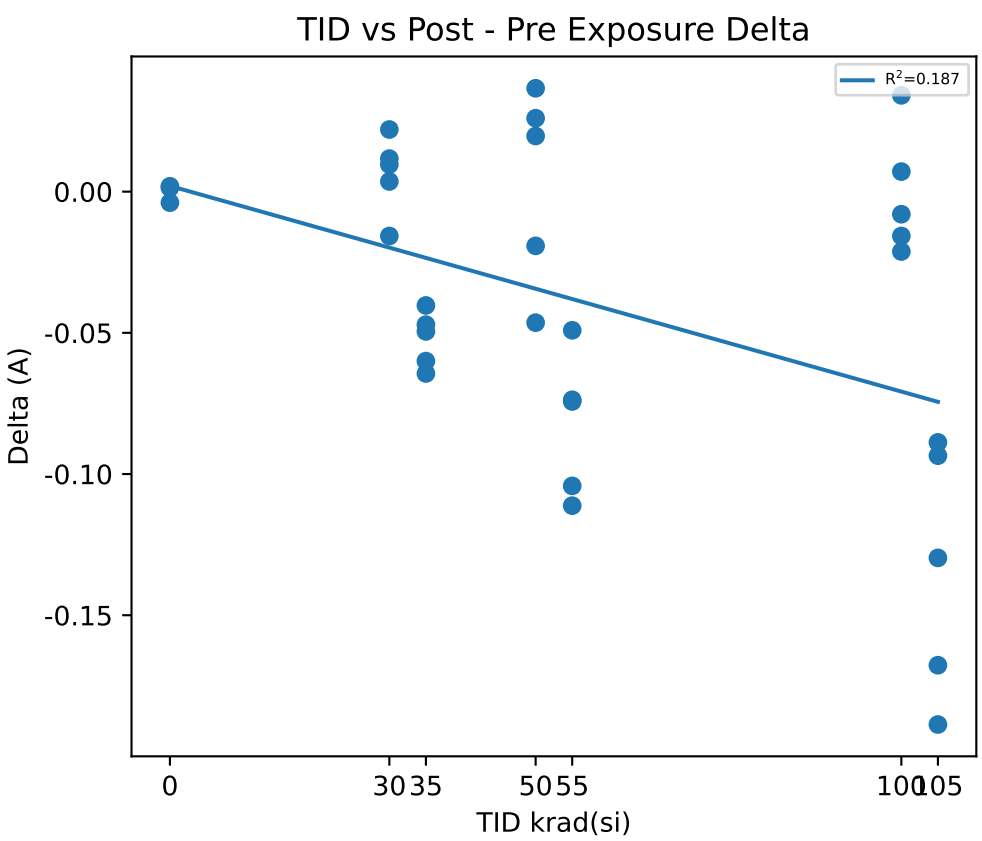
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.7788	2.7792	0.0004
2	0	CU2	2.8582	2.8531	-0.0051
3	0	CU3	2.829	2.829	0
11	30	Unbiased-30krad	2.8941	2.8748	-0.0193
12	30	Unbiased-30krad	3.1228	3.1029	-0.0199
13	30	Unbiased-30krad	2.9036	2.8776	-0.026
14	30	Unbiased-30krad	2.8681	2.861	-0.0071
15	30	Unbiased-30krad	2.6971	2.6792	-0.0179
16	35	Biased-30krad	2.9186	2.8365	-0.0821
17	35	Biased-30krad	2.8728	2.7717	-0.1011
18	35	Biased-30krad	3.0924	2.997	-0.0954
19	35	Biased-30krad	2.9625	2.8733	-0.0892
20	35	Biased-30krad	2.7192	2.6397	-0.0795
30	50	Unbiased-50krad	2.9858	2.9543	-0.0315
31	50	Unbiased-50krad	2.9269	2.9025	-0.0244
32	50	Unbiased-50krad	2.801	2.7816	-0.0194
33	50	Unbiased-50krad	2.7516	2.7235	-0.0281
34	50	Unbiased-50krad	2.718	2.6852	-0.0328
40	55	Biased-50krad	2.998	2.863	-0.135
41	55	Biased-50krad	2.9534	2.8085	-0.1449
42	55	Biased-50krad	2.9494	2.8057	-0.1437
43	55	Biased-50krad	2.6983	2.5761	-0.1222
44	55	Biased-50krad	2.8325	2.701	-0.1315
45	100	Unbiased-100krad	2.8819	2.8211	-0.0608
46	100	Unbiased-100krad	2.9052	2.8646	-0.0406
47	100	Unbiased-100krad	2.8535	2.799	-0.0545
48	100	Unbiased-100krad	2.8989	2.8515	-0.0474
49	100	Unbiased-100krad	2.7769	2.7547	-0.0222
50	105	Biased-100krad	2.9257	2.718	-0.2077
51	105	Biased-100krad	2.7871	2.5935	-0.1936
52	105	Biased-100krad	2.9396	2.7259	-0.2137
53	105	Biased-100krad	2.7875	2.5757	-0.2118
54	105	Biased-100krad	2.8456	2.6385	-0.2071

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7788	2.822	2.8582	0.04016	2.7792	2.8204	2.8531	0.037687	-0.0051	-0.0015667	0.0004	0.0030665
30	2.6971	2.8971	3.1228	0.15152	2.6792	2.8791	3.1029	0.15033	-0.026	-0.01804	-0.0071	0.0068577
35	2.7192	2.9131	3.0924	0.13587	2.6397	2.8236	2.997	0.13155	-0.1011	-0.08946	-0.0795	0.0090029
50	2.718	2.8367	2.9858	0.11508	2.6852	2.8094	2.9543	0.11537	-0.0328	-0.02724	-0.0194	0.005462
55	2.6983	2.8863	2.998	0.12165	2.5761	2.7509	2.863	0.11394	-0.1449	-0.13546	-0.1222	0.0093372
100	2.7769	2.8633	2.9052	0.052273	2.7547	2.8182	2.8646	0.043793	-0.0608	-0.0451	-0.0222	0.014873
105	2.7871	2.8571	2.9396	0.073124	2.5757	2.6503	2.7259	0.069335	-0.2137	-0.20678	-0.1936	0.00787

Device Test: 29.2 _ILIM_LS|LS_Sourcing/SW1/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





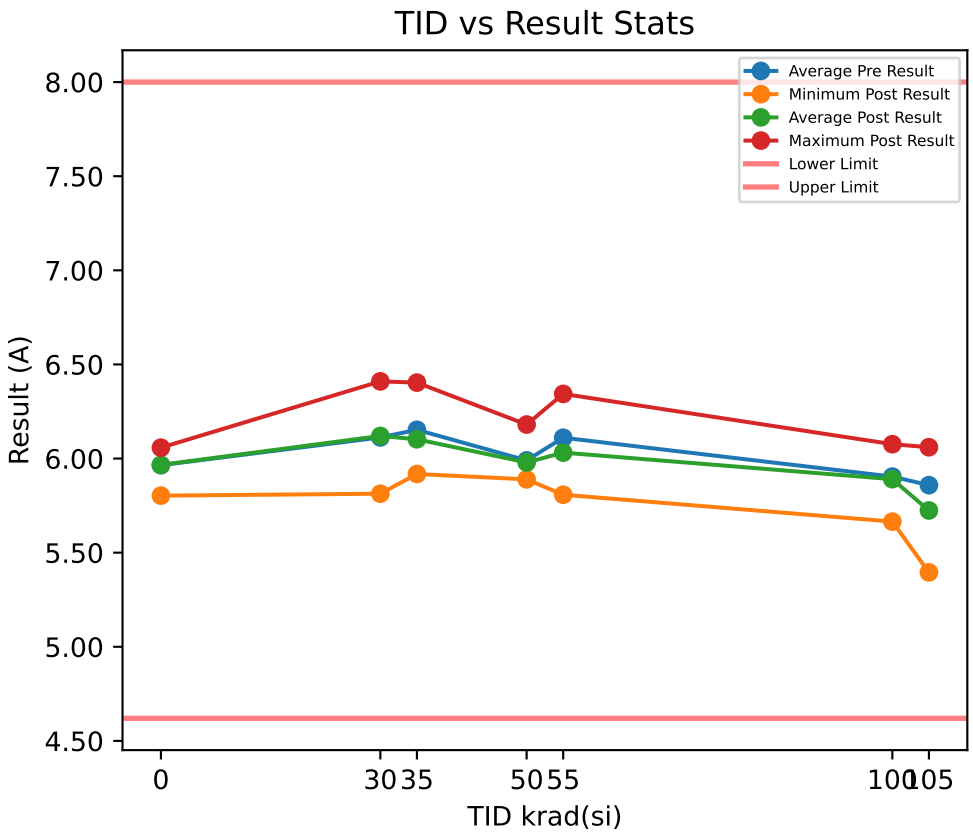
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

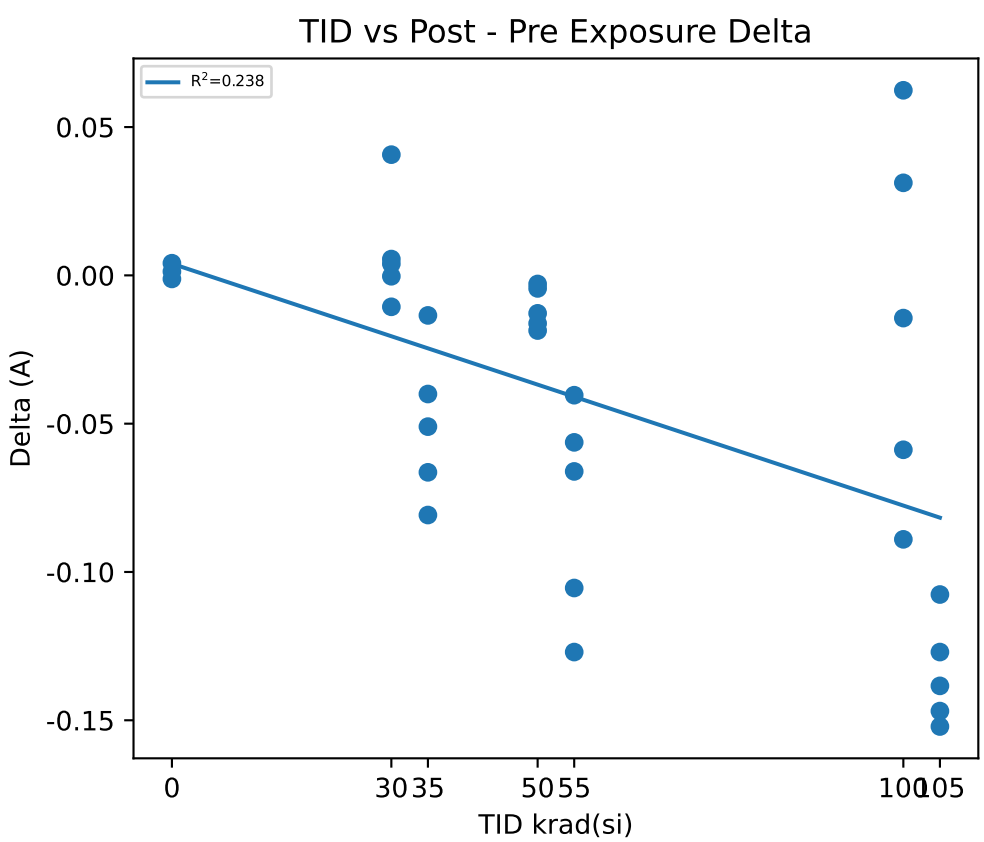
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.049	6.0451	-0.0039
2	0	CU2	6.2064	6.2083	0.0019
3	0	CU3	6.1516	6.153	0.0014
11	30	Unbiased-30krad	6.1114	6.121	0.0096
12	30	Unbiased-30krad	6.2641	6.2861	0.022
13	30	Unbiased-30krad	6.3418	6.3454	0.0036
14	30	Unbiased-30krad	6.049	6.0333	-0.0157
15	30	Unbiased-30krad	5.9015	5.9132	0.0117
16	35	Biased-30krad	6.3872	6.3228	-0.0644
17	35	Biased-30krad	6.0459	5.9859	-0.06
18	35	Biased-30krad	6.18	6.1305	-0.0495
19	35	Biased-30krad	6.3217	6.2746	-0.0471
20	35	Biased-30krad	5.9456	5.9053	-0.0403
30	50	Unbiased-50krad	5.8766	5.9132	0.0366
31	50	Unbiased-50krad	5.9614	5.9811	0.0197
32	50	Unbiased-50krad	5.8798	5.8334	-0.0464
33	50	Unbiased-50krad	6.182	6.1628	-0.0192
34	50	Unbiased-50krad	5.9717	5.9977	0.026
40	55	Biased-50krad	6.1796	6.0684	-0.1112
41	55	Biased-50krad	6.0873	5.9831	-0.1042
42	55	Biased-50krad	6.0691	5.9954	-0.0737
43	55	Biased-50krad	5.6896	5.6153	-0.0743
44	55	Biased-50krad	6.1796	6.1305	-0.0491
45	100	Unbiased-100krad	6.1114	6.1455	0.0341
46	100	Unbiased-100krad	6.0214	6.0285	0.0071
47	100	Unbiased-100krad	5.7787	5.7575	-0.0212
48	100	Unbiased-100krad	6.0968	6.0811	-0.0157
49	100	Unbiased-100krad	5.8683	5.8603	-0.008
50	105	Biased-100krad	6.1915	6.0238	-0.1677
51	105	Biased-100krad	5.7365	5.6477	-0.0888
52	105	Biased-100krad	5.7665	5.5778	-0.1887
53	105	Biased-100krad	5.7511	5.6576	-0.0935
54	105	Biased-100krad	5.8924	5.7627	-0.1297

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.049	6.1357	6.2064	0.079901	6.0451	6.1355	6.2083	0.083001	-0.0039	-0.0002	0.0019	0.003214
30	5.9015	6.1336	6.3418	0.17457	5.9132	6.1398	6.3454	0.17799	-0.0157	0.00624	0.022	0.013945
35	5.9456	6.1761	6.3872	0.1843	5.9053	6.1238	6.3228	0.17968	-0.0644	-0.05226	-0.0403	0.0098053
50	5.8766	5.9743	6.182	0.12429	5.8334	5.9776	6.1628	0.12212	-0.0464	0.00334	0.0366	0.034891
55	5.6896	6.041	6.1796	0.203	5.6153	5.9585	6.1305	0.20088	-0.1112	-0.0825	-0.0491	0.025273
100	5.7787	5.9753	6.1114	0.14621	5.7575	5.9746	6.1455	0.16097	-0.0212	-0.00074	0.0341	0.022195
105	5.7365	5.8676	6.1915	0.19138	5.5778	5.7339	6.0238	0.17499	-0.1887	-0.13368	-0.0888	0.044241

Device Test: 29.3 _ILIM_LS|LS_Sourcing/SW2/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





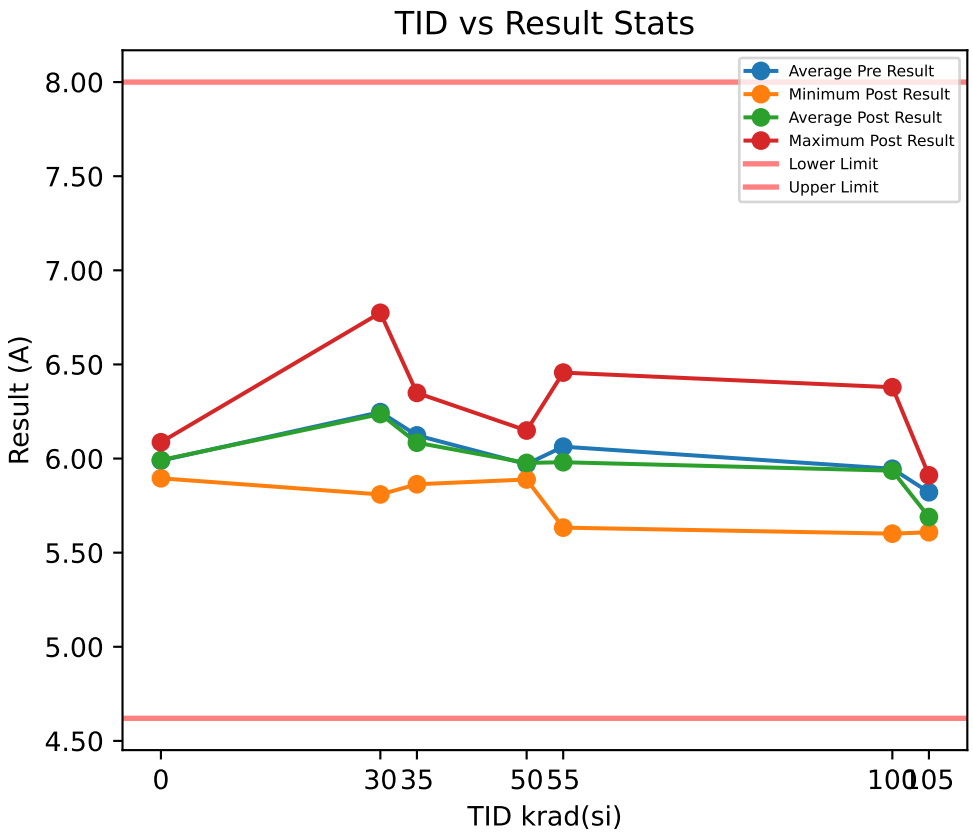
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

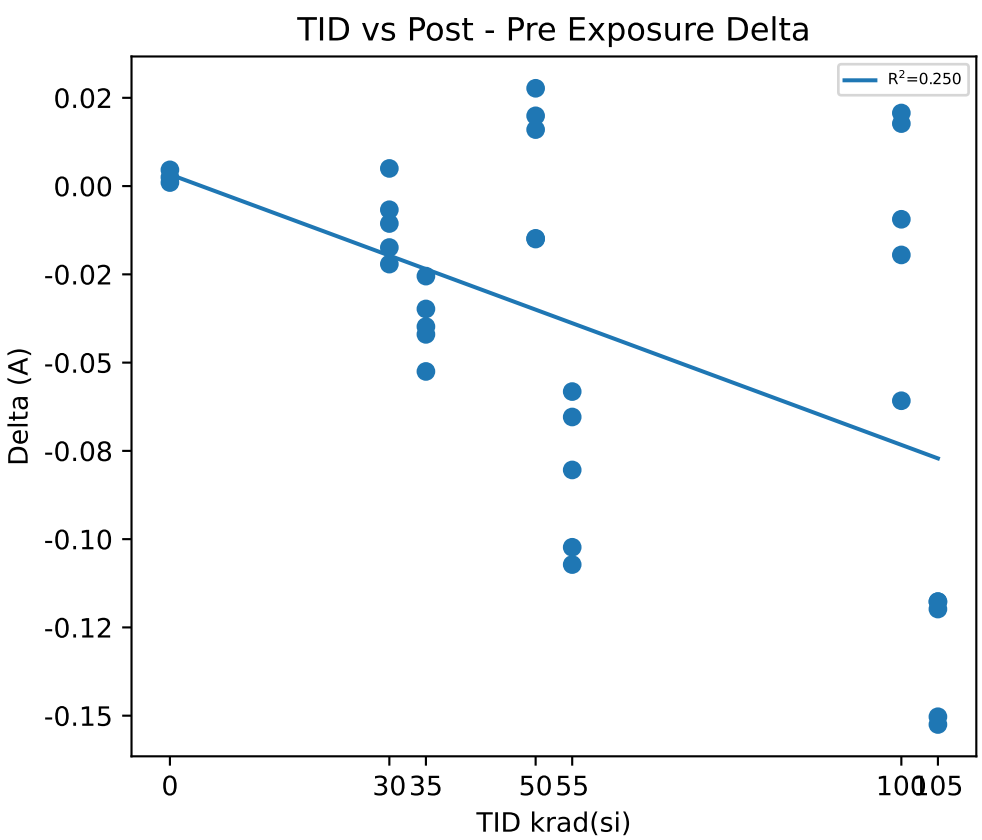
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0565	6.0578	0.0013
2	0	CU2	5.7989	5.803	0.0041
3	0	CU3	6.0392	6.038	-0.0012
11	30	Unbiased-30krad	6.2944	6.2983	0.0039
12	30	Unbiased-30krad	5.8135	5.8132	-0.0003
13	30	Unbiased-30krad	6.3694	6.4101	0.0407
14	30	Unbiased-30krad	6.0964	6.0858	-0.0106
15	30	Unbiased-30krad	5.9871	5.9926	0.0055
16	35	Biased-30krad	6.3146	6.2746	-0.04
17	35	Biased-30krad	5.9689	5.9179	-0.051
18	35	Biased-30krad	5.9867	5.9732	-0.0135
19	35	Biased-30krad	6.0092	5.9428	-0.0664
20	35	Biased-30krad	6.4842	6.4034	-0.0808
30	50	Unbiased-50krad	5.9389	5.9203	-0.0186
31	50	Unbiased-50krad	6.0021	5.9977	-0.0044
32	50	Unbiased-50krad	5.9239	5.9077	-0.0162
33	50	Unbiased-50krad	6.1934	6.1806	-0.0128
34	50	Unbiased-50krad	5.8924	5.8895	-0.0029
40	55	Biased-50krad	5.9141	5.848	-0.0661
41	55	Biased-50krad	6.3749	6.2695	-0.1054
42	55	Biased-50krad	6.4704	6.3434	-0.127
43	55	Biased-50krad	5.9295	5.8891	-0.0404
44	55	Biased-50krad	5.864	5.8077	-0.0563
45	100	Unbiased-100krad	5.8987	5.8843	-0.0144
46	100	Unbiased-100krad	5.9441	5.8551	-0.089
47	100	Unbiased-100krad	5.7239	5.6651	-0.0588
48	100	Unbiased-100krad	6.0139	6.0763	0.0624
49	100	Unbiased-100krad	5.9397	5.9709	0.0312
50	105	Biased-100krad	6.1871	6.0601	-0.127
51	105	Biased-100krad	5.6036	5.496	-0.1076
52	105	Biased-100krad	5.5337	5.3953	-0.1384
53	105	Biased-100krad	5.9642	5.8121	-0.1521
54	105	Biased-100krad	6.0044	5.8575	-0.1469

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7989	5.9649	6.0565	0.14399	5.803	5.9663	6.0578	0.14174	-0.0012	0.0014	0.0041	0.0026514
30	5.8135	6.1122	6.3694	0.22609	5.8132	6.12	6.4101	0.23847	-0.0106	0.00784	0.0407	0.019411
35	5.9689	6.1527	6.4842	0.23347	5.9179	6.1024	6.4034	0.22162	-0.0808	-0.05034	-0.0135	0.02574
50	5.8924	5.9901	6.1934	0.12044	5.8895	5.9792	6.1806	0.11993	-0.0186	-0.01098	-0.0029	0.0070215
55	5.864	6.1106	6.4704	0.28789	5.8077	6.0315	6.3434	0.25395	-0.127	-0.07904	-0.0404	0.03596
100	5.7239	5.9041	6.0139	0.10889	5.6651	5.8903	6.0763	0.15255	-0.089	-0.01372	0.0624	0.062273
105	5.5337	5.8586	6.1871	0.27879	5.3953	5.7242	6.0601	0.27321	-0.1521	-0.1344	-0.1076	0.017738

Device Test: 29.4 _ILIM_LS|LS_Sourcing/SW3/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





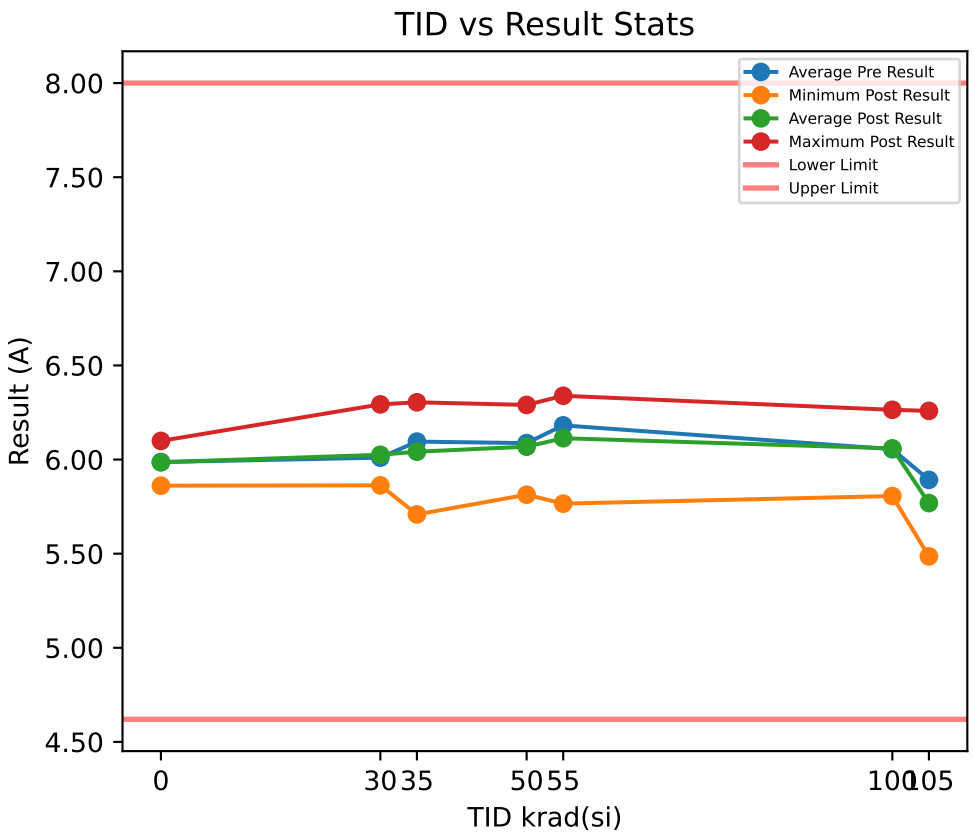
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

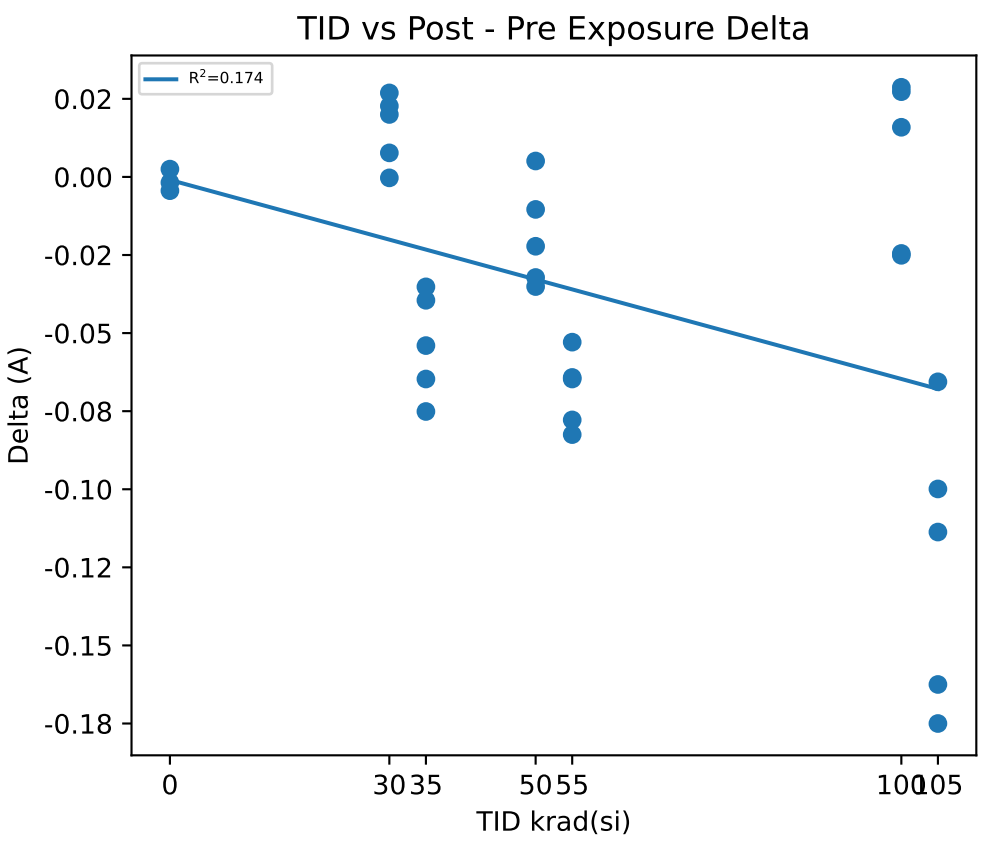
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8941	5.8951	0.001
2	0	CU2	5.9913	5.9938	0.0025
3	0	CU3	6.0821	6.0867	0.0046
11	30	Unbiased-30krad	6.334	6.3234	-0.0106
12	30	Unbiased-30krad	6.7917	6.7743	-0.0174
13	30	Unbiased-30krad	6.2633	6.2412	-0.0221
14	30	Unbiased-30krad	6.0284	6.0334	0.005
15	30	Unbiased-30krad	5.816	5.8093	-0.0067
16	35	Biased-30krad	6.0185	5.9765	-0.042
17	35	Biased-30krad	6.077	6.0515	-0.0255
18	35	Biased-30krad	6.2156	6.1808	-0.0348
19	35	Biased-30krad	6.4012	6.3487	-0.0525
20	35	Biased-30krad	5.9032	5.8634	-0.0398
30	50	Unbiased-50krad	5.921	5.9409	0.0199
31	50	Unbiased-50krad	5.861	5.8887	0.0277
32	50	Unbiased-50krad	5.8783	5.8943	0.016
33	50	Unbiased-50krad	6.026	6.0112	-0.0148
34	50	Unbiased-50krad	6.1638	6.1488	-0.015
40	55	Biased-50krad	6.2183	6.116	-0.1023
41	55	Biased-50krad	5.9411	5.8607	-0.0804
42	55	Biased-50krad	6.5638	6.4566	-0.1072
43	55	Biased-50krad	5.6912	5.633	-0.0582
44	55	Biased-50krad	5.9012	5.8358	-0.0654
45	100	Unbiased-100krad	5.6509	5.6686	0.0177
46	100	Unbiased-100krad	5.6205	5.601	-0.0195
47	100	Unbiased-100krad	5.8254	5.816	-0.0094
48	100	Unbiased-100krad	6.3581	6.3788	0.0207
49	100	Unbiased-100krad	6.2744	6.2136	-0.0608
50	105	Biased-100krad	5.7962	5.6785	-0.1177
51	105	Biased-100krad	5.7283	5.6085	-0.1198
52	105	Biased-100krad	5.7484	5.6307	-0.1177
53	105	Biased-100krad	5.7705	5.618	-0.1525
54	105	Biased-100krad	6.0612	5.9109	-0.1503

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8941	5.9892	6.0821	0.094018	5.8951	5.9919	6.0867	0.095815	0.001	0.0027	0.0046	0.0018083
30	5.816	6.2467	6.7917	0.36677	5.8093	6.2363	6.7743	0.36075	-0.0221	-0.01036	0.005	0.01045
35	5.9032	6.1231	6.4012	0.19191	5.8634	6.0842	6.3487	0.18756	-0.0525	-0.03892	-0.0255	0.0098963
50	5.861	5.97	6.1638	0.12588	5.8887	5.9768	6.1488	0.10796	-0.015	0.00676	0.0277	0.020217
55	5.6912	6.0631	6.5638	0.33697	5.633	5.9804	6.4566	0.31665	-0.1072	-0.0827	-0.0582	0.021733
100	5.6205	5.9459	6.3581	0.3483	5.601	5.9356	6.3788	0.34324	-0.0608	-0.01026	0.0207	0.033093
105	5.7283	5.8209	6.0612	0.13668	5.6085	5.6893	5.9109	0.12676	-0.1525	-0.1316	-0.1177	0.018112

Device Test: 29.5 _ILIM_LS|LS_Sourcing/SW4/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





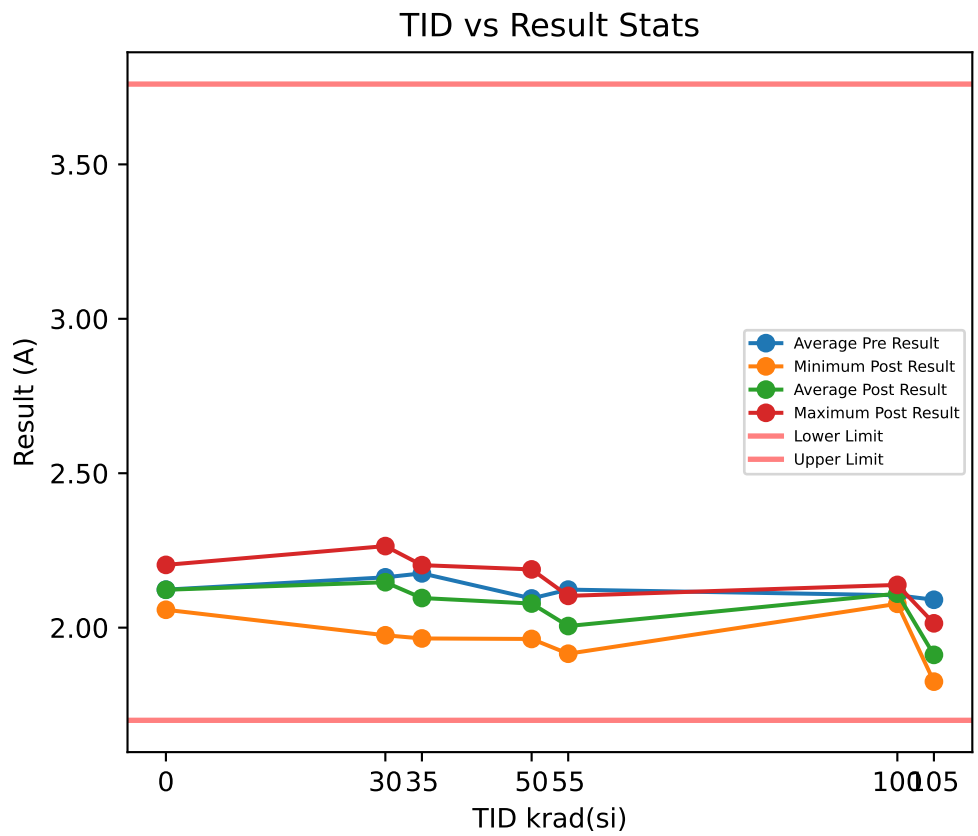
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

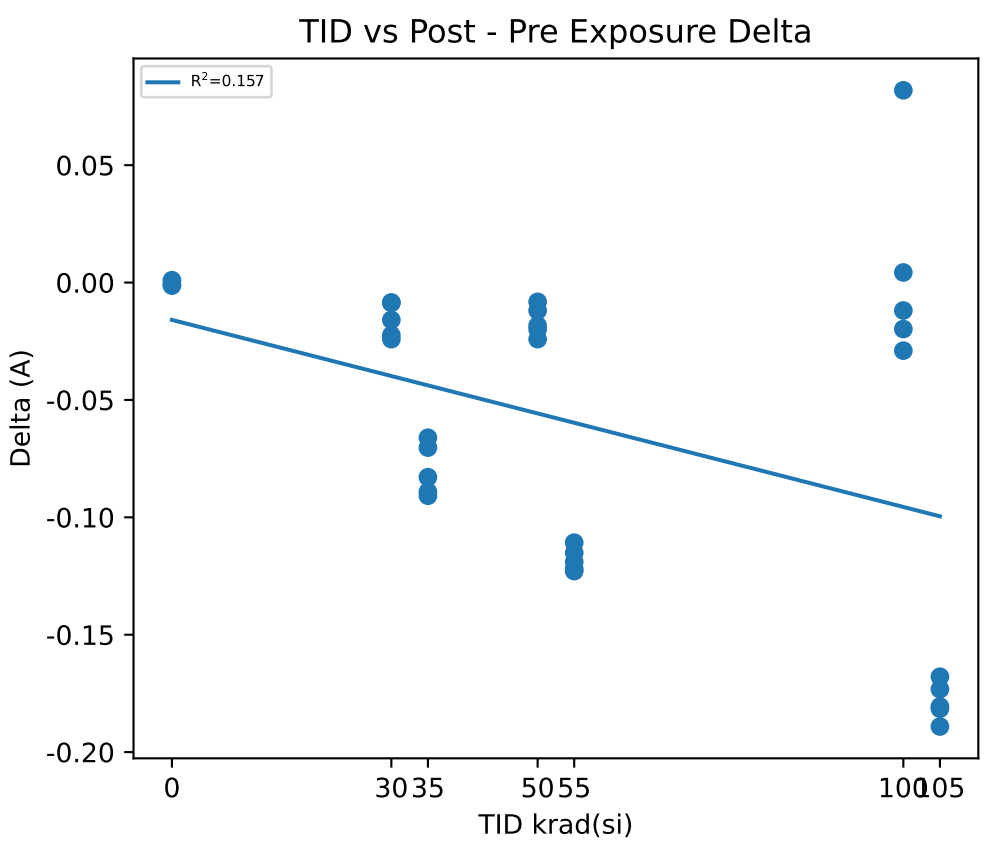
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9984	5.9966	-0.0018
2	0	CU2	5.8586	5.8611	0.0025
3	0	CU3	6.1034	6.099	-0.0044
11	30	Unbiased-30krad	5.9506	5.9583	0.0077
12	30	Unbiased-30krad	5.9814	6.0014	0.02
13	30	Unbiased-30krad	6.2661	6.293	0.0269
14	30	Unbiased-30krad	5.8633	5.863	-0.0003
15	30	Unbiased-30krad	5.9885	6.0112	0.0227
16	35	Biased-30krad	6.3688	6.3041	-0.0647
17	35	Biased-30krad	6.2586	6.1835	-0.0751
18	35	Biased-30krad	6.2108	6.1713	-0.0395
19	35	Biased-30krad	5.8945	5.8405	-0.054
20	35	Biased-30krad	5.7437	5.7085	-0.0352
30	50	Unbiased-50krad	6.2851	6.2902	0.0051
31	50	Unbiased-50krad	6.1982	6.176	-0.0222
32	50	Unbiased-50krad	6.0691	6.0587	-0.0104
33	50	Unbiased-50krad	6.0359	6.0037	-0.0322
34	50	Unbiased-50krad	5.8483	5.8132	-0.0351
40	55	Biased-50krad	6.304	6.2262	-0.0778
41	55	Biased-50krad	6.3937	6.329	-0.0647
42	55	Biased-50krad	6.3917	6.3388	-0.0529
43	55	Biased-50krad	5.9707	5.9065	-0.0642
44	55	Biased-50krad	5.8483	5.7658	-0.0825
45	100	Unbiased-100krad	6.2807	6.2562	-0.0245
46	100	Unbiased-100krad	5.9012	5.8761	-0.0251
47	100	Unbiased-100krad	5.7788	5.8061	0.0273
48	100	Unbiased-100krad	6.2483	6.2642	0.0159
49	100	Unbiased-100krad	6.0659	6.0946	0.0287
50	105	Biased-100krad	6.3585	6.2586	-0.0999
51	105	Biased-100krad	5.6485	5.5829	-0.0656
52	105	Biased-100krad	5.8894	5.7757	-0.1137
53	105	Biased-100krad	5.6481	5.4856	-0.1625
54	105	Biased-100krad	5.9159	5.7409	-0.175

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8586	5.9868	6.1034	0.12281	5.8611	5.9856	6.099	0.11933	-0.0044	-0.0012333	0.0025	0.0034847
30	5.8633	6.01	6.2661	0.15159	5.863	6.0254	6.293	0.16067	-0.0003	0.0154	0.0269	0.011319
35	5.7437	6.0953	6.3688	0.26399	5.7085	6.0416	6.3041	0.2536	-0.0751	-0.0537	-0.0352	0.016755
50	5.8483	6.0873	6.2851	0.16697	5.8132	6.0684	6.2902	0.1804	-0.0351	-0.01896	0.0051	0.016571
55	5.8483	6.1817	6.3937	0.25479	5.7658	6.1133	6.3388	0.26156	-0.0825	-0.06842	-0.0529	0.011819
100	5.7788	6.055	6.2807	0.21701	5.8061	6.0594	6.2642	0.21194	-0.0251	0.00446	0.0287	0.027169
105	5.6481	5.8921	6.3585	0.29025	5.4856	5.7687	6.2586	0.29812	-0.175	-0.12334	-0.0656	0.045218

Device Test: 29.6 _ILIM_LS|LS_Sinking/SW1/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK





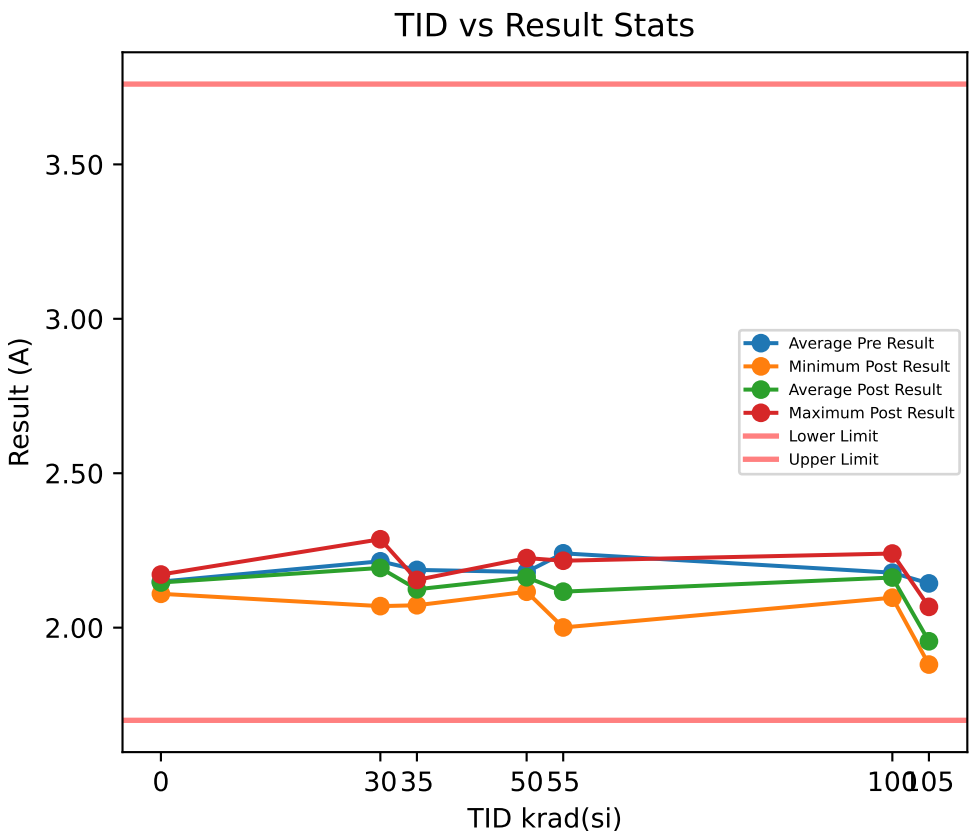
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

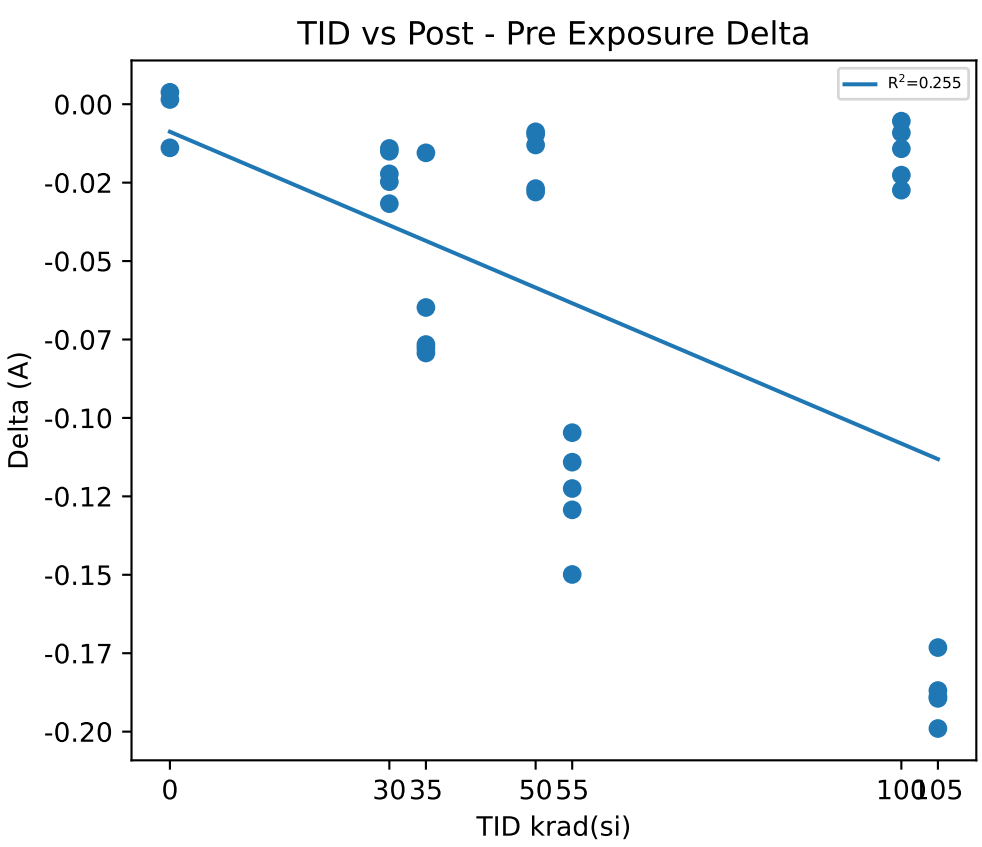
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1058	2.1068	0.001
2	0	CU2	2.204	2.2032	-0.0008
3	0	CU3	2.0592	2.0579	-0.0013
11	30	Unbiased-30krad	2.1685	2.1444	-0.0241
12	30	Unbiased-30krad	2.2865	2.2641	-0.0224
13	30	Unbiased-30krad	2.245	2.2364	-0.0086
14	30	Unbiased-30krad	2.131	2.1151	-0.0159
15	30	Unbiased-30krad	1.9838	1.9753	-0.0085
16	35	Biased-30krad	2.2482	2.1574	-0.0908
17	35	Biased-30krad	2.0592	1.9931	-0.0661
18	35	Biased-30krad	2.232	2.1617	-0.0703
19	35	Biased-30krad	2.2853	2.2024	-0.0829
20	35	Biased-30krad	2.0541	1.965	-0.0891
30	50	Unbiased-50krad	2.1397	2.1278	-0.0119
31	50	Unbiased-50krad	2.0671	2.0472	-0.0199
32	50	Unbiased-50krad	1.9716	1.9634	-0.0082
33	50	Unbiased-50krad	2.2127	2.1886	-0.0241
34	50	Unbiased-50krad	2.0817	2.0634	-0.0183
40	55	Biased-50krad	2.2249	2.1029	-0.122
41	55	Biased-50krad	2.1156	1.9927	-0.1229
42	55	Biased-50krad	2.1772	2.0582	-0.119
43	55	Biased-50krad	2.0264	1.9156	-0.1108
44	55	Biased-50krad	2.0718	1.9567	-0.1151
45	100	Unbiased-100krad	2.1503	2.1384	-0.0119
46	100	Unbiased-100krad	2.1065	2.1108	0.0043
47	100	Unbiased-100krad	2.1062	2.0772	-0.029
48	100	Unbiased-100krad	2.144	2.1242	-0.0198
49	100	Unbiased-100krad	2.0178	2.0997	0.0819
50	105	Biased-100krad	2.1819	2.014	-0.1679
51	105	Biased-100krad	1.9984	1.8252	-0.1732
52	105	Biased-100krad	2.0403	1.8512	-0.1891
53	105	Biased-100krad	2.1062	1.9247	-0.1815
54	105	Biased-100krad	2.1247	1.9441	-0.1806

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0592	2.123	2.204	0.073916	2.0579	2.1226	2.2032	0.073933	-0.0013	-0.00036667	0.001	0.0012097
30	1.9838	2.163	2.2865	0.11741	1.9753	2.1471	2.2641	0.11425	-0.0241	-0.0159	-0.0085	0.0073746
35	2.0541	2.1758	2.2853	0.11045	1.965	2.0959	2.2024	0.10858	-0.0908	-0.07984	-0.0661	0.011125
50	1.9716	2.0946	2.2127	0.089489	1.9634	2.0781	2.1886	0.085158	-0.0241	-0.01648	-0.0082	0.0063759
55	2.0264	2.1232	2.2249	0.079575	1.9156	2.0052	2.1029	0.075649	-0.1229	-0.11796	-0.1108	0.0050312
100	2.0178	2.105	2.1503	0.052869	2.0772	2.1101	2.1384	0.023403	-0.029	0.0051	0.0819	0.044639
105	1.9984	2.0903	2.1819	0.072063	1.8252	1.9118	2.014	0.075542	-0.1891	-0.17846	-0.1679	0.008158

Device Test: 29.7 _ILIM_LS|LS_Sinking/SW2/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK





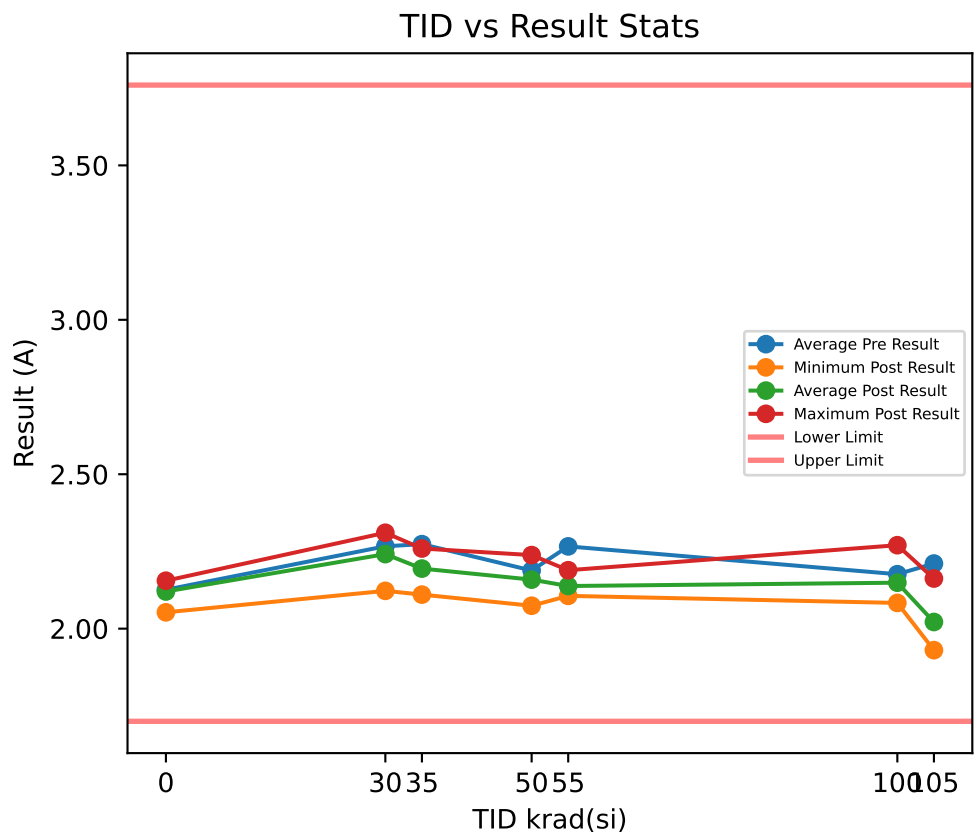
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

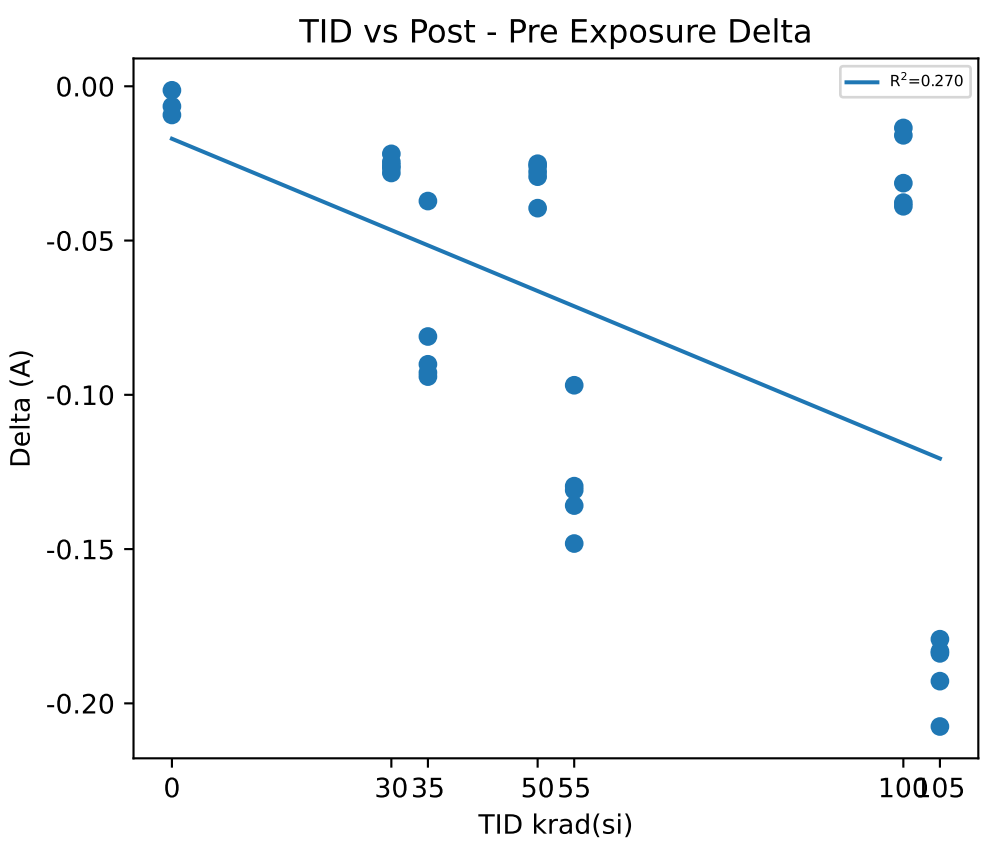
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1555	2.157	0.0015
2	0	CU2	2.1058	2.1096	0.0038
3	0	CU3	2.1859	2.172	-0.0139
11	30	Unbiased-30krad	2.2908	2.2767	-0.0141
12	30	Unbiased-30krad	2.1073	2.0851	-0.0222
13	30	Unbiased-30krad	2.3109	2.2862	-0.0247
14	30	Unbiased-30krad	2.264	2.249	-0.015
15	30	Unbiased-30krad	2.1014	2.0697	-0.0317
16	35	Biased-30krad	2.2032	2.1384	-0.0648
17	35	Biased-30krad	2.1898	2.112	-0.0778
18	35	Biased-30krad	2.088	2.0725	-0.0155
19	35	Biased-30krad	2.2312	2.1546	-0.0766
20	35	Biased-30krad	2.2225	2.1432	-0.0793
30	50	Unbiased-50krad	2.1259	2.1163	-0.0096
31	50	Unbiased-50krad	2.1417	2.1329	-0.0088
32	50	Unbiased-50krad	2.193	2.1661	-0.0269
33	50	Unbiased-50krad	2.2533	2.2253	-0.028
34	50	Unbiased-50krad	2.1882	2.1752	-0.013
40	55	Biased-50krad	2.1969	2.0922	-0.1047
41	55	Biased-50krad	2.346	2.2167	-0.1293
42	55	Biased-50krad	2.3654	2.2155	-0.1499
43	55	Biased-50krad	2.172	2.0579	-0.1141
44	55	Biased-50krad	2.1231	2.0006	-0.1225
45	100	Unbiased-100krad	2.1882	2.1791	-0.0091
46	100	Unbiased-100krad	2.1196	2.097	-0.0226
47	100	Unbiased-100krad	2.1271	2.0997	-0.0274
48	100	Unbiased-100krad	2.2454	2.24	-0.0054
49	100	Unbiased-100krad	2.2099	2.1957	-0.0142
50	105	Biased-100krad	2.2663	2.0673	-0.199
51	105	Biased-100krad	2.088	1.9148	-0.1732
52	105	Biased-100krad	2.0699	1.8805	-0.1894
53	105	Biased-100krad	2.0773	1.8904	-0.1869
54	105	Biased-100krad	2.215	2.0262	-0.1888

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1058	2.1491	2.1859	0.040436	2.1096	2.1462	2.172	0.032572	-0.0139	-0.0028667	0.0038	0.0096241
30	2.1014	2.2149	2.3109	0.10228	2.0697	2.1933	2.2862	0.10686	-0.0317	-0.02154	-0.0141	0.0072762
35	2.088	2.1869	2.2312	0.057631	2.0725	2.1241	2.1546	0.03282	-0.0793	-0.0628	-0.0155	0.02706
50	2.1259	2.1804	2.2533	0.050005	2.1163	2.1632	2.2253	0.042209	-0.028	-0.01726	-0.0088	0.0094429
55	2.1231	2.2407	2.3654	0.10852	2.0006	2.1166	2.2167	0.096564	-0.1499	-0.1241	-0.1047	0.017114
100	2.1196	2.178	2.2454	0.054004	2.097	2.1623	2.24	0.062486	-0.0274	-0.01574	-0.0054	0.0091705
105	2.0699	2.1433	2.2663	0.090928	1.8805	1.9558	2.0673	0.085171	-0.199	-0.18746	-0.1732	0.0092519

Device Test: 29.8 _ILIM_LS|LS_Sinking/SW3/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK





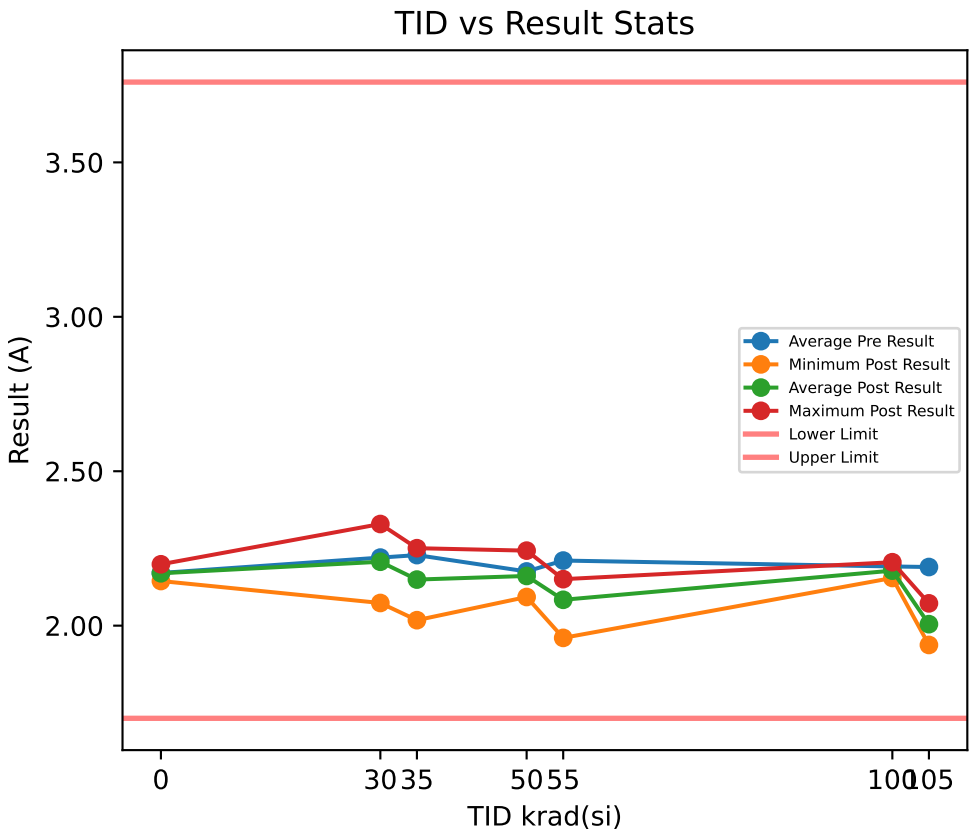
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

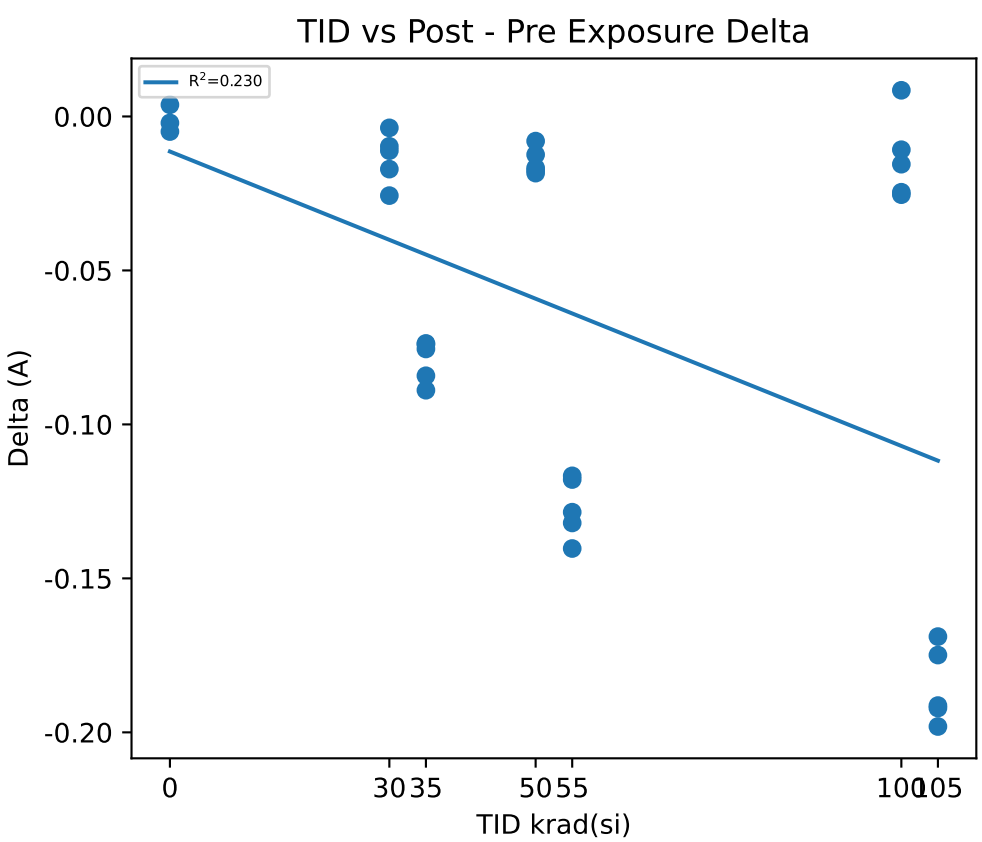
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1565	2.1552	-0.0013
2	0	CU2	2.1593	2.1528	-0.0065
3	0	CU3	2.0622	2.0529	-0.0093
11	30	Unbiased-30krad	2.2766	2.2501	-0.0265
12	30	Unbiased-30krad	2.2473	2.2228	-0.0245
13	30	Unbiased-30krad	2.3362	2.3105	-0.0257
14	30	Unbiased-30krad	2.3291	2.301	-0.0281
15	30	Unbiased-30krad	2.1443	2.1224	-0.0219
16	35	Biased-30krad	2.3255	2.2327	-0.0928
17	35	Biased-30krad	2.2805	2.1904	-0.0901
18	35	Biased-30krad	2.2967	2.2595	-0.0372
19	35	Biased-30krad	2.2608	2.1797	-0.0811
20	35	Biased-30krad	2.2043	2.1102	-0.0941
30	50	Unbiased-50krad	2.1297	2.1046	-0.0251
31	50	Unbiased-50krad	2.1001	2.0742	-0.0259
32	50	Unbiased-50krad	2.1877	2.16	-0.0277
33	50	Unbiased-50krad	2.2564	2.2169	-0.0395
34	50	Unbiased-50krad	2.2675	2.2382	-0.0293
40	55	Biased-50krad	2.2714	2.1418	-0.1296
41	55	Biased-50krad	2.2592	2.1283	-0.1309
42	55	Biased-50krad	2.3251	2.1892	-0.1359
43	55	Biased-50krad	2.2031	2.1062	-0.0969
44	55	Biased-50krad	2.273	2.1248	-0.1482
45	100	Unbiased-100krad	2.1332	2.0955	-0.0377
46	100	Unbiased-100krad	2.1147	2.0833	-0.0314
47	100	Unbiased-100krad	2.1577	2.1418	-0.0159
48	100	Unbiased-100krad	2.2837	2.2702	-0.0135
49	100	Unbiased-100krad	2.1921	2.1532	-0.0389
50	105	Biased-100krad	2.3551	2.1623	-0.1928
51	105	Biased-100krad	2.1514	1.9722	-0.1792
52	105	Biased-100krad	2.1135	1.9304	-0.1831
53	105	Biased-100krad	2.1778	1.994	-0.1838
54	105	Biased-100krad	2.2564	2.0489	-0.2075

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0622	2.126	2.1593	0.05527	2.0529	2.1203	2.1552	0.058382	-0.0093	-0.0057	-0.0013	0.0040596
30	2.1443	2.2667	2.3362	0.07775	2.1224	2.2414	2.3105	0.07568	-0.0281	-0.02534	-0.0219	0.0023255
35	2.2043	2.2736	2.3255	0.04539	2.1102	2.1945	2.2595	0.057067	-0.0941	-0.07906	-0.0372	0.023944
50	2.1001	2.1883	2.2675	0.07437	2.0742	2.1588	2.2382	0.070314	-0.0395	-0.0295	-0.0251	0.0058224
55	2.2031	2.2664	2.3251	0.043511	2.1062	2.1381	2.1892	0.031287	-0.1482	-0.1283	-0.0969	0.019027
100	2.1147	2.1763	2.2837	0.066676	2.0833	2.1488	2.2702	0.074056	-0.0389	-0.02748	-0.0135	0.012039
105	2.1135	2.2108	2.3551	0.096159	1.9304	2.0216	2.1623	0.089528	-0.2075	-0.18928	-0.1792	0.011338

Device Test: 29.9 _ILIM_LS|LS_Sinking/SW4/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK





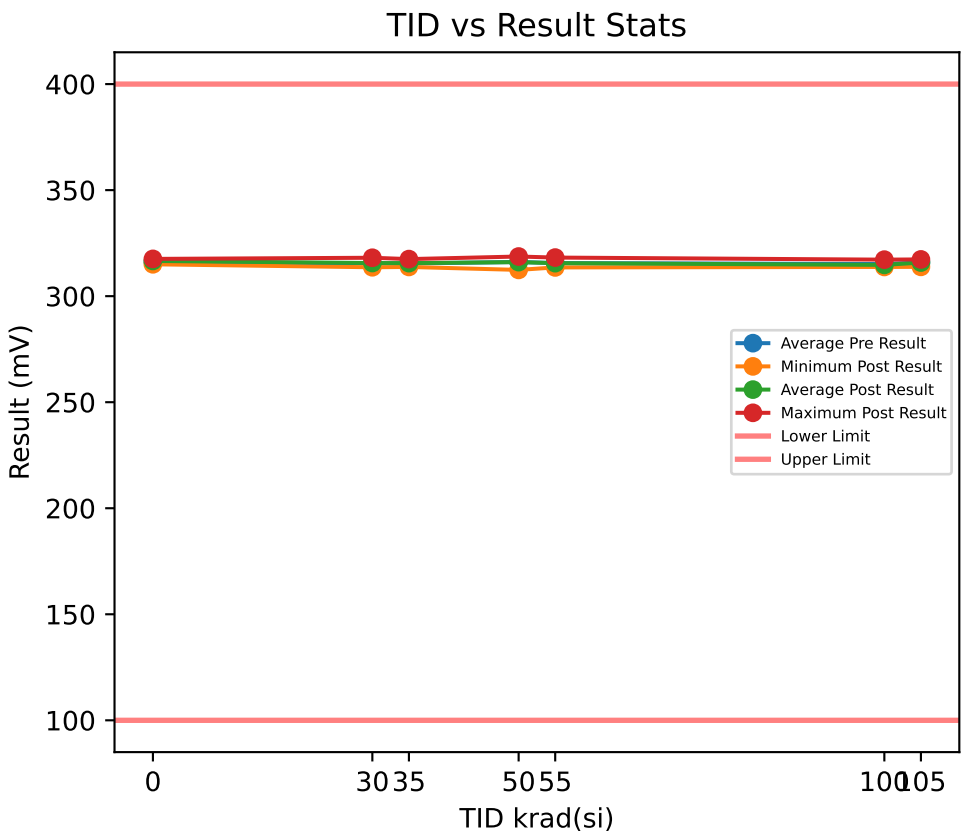
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

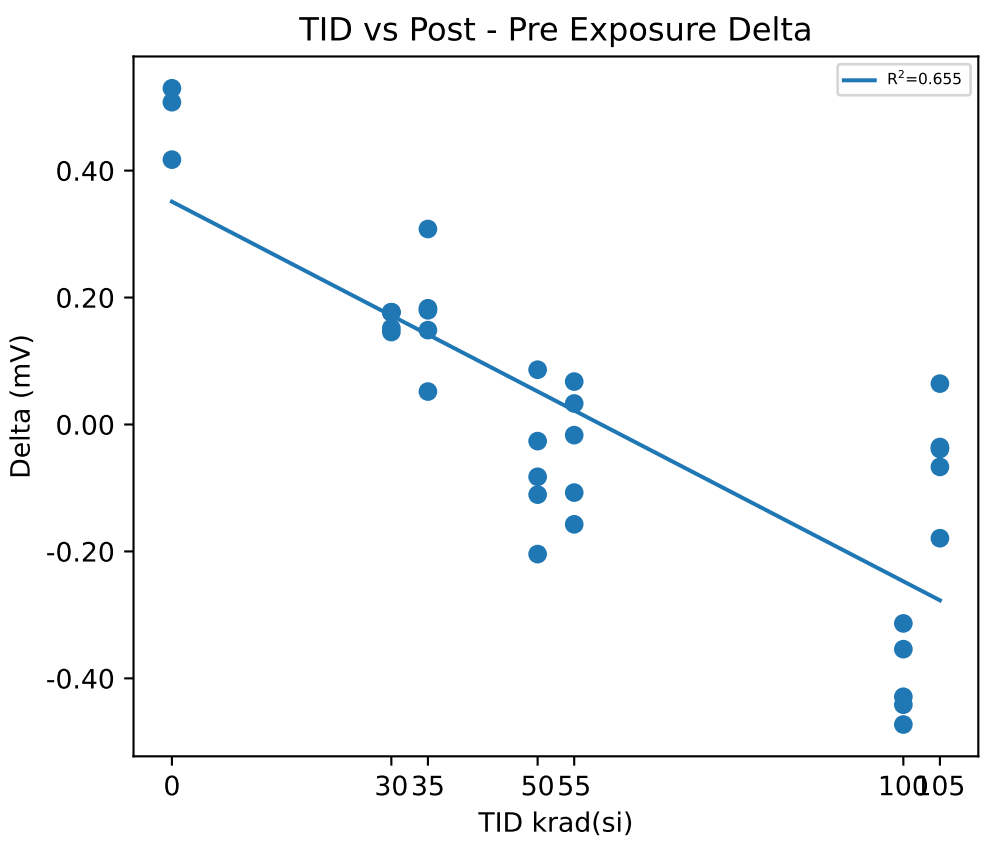
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1494	2.1445	-0.0049
2	0	CU2	2.1617	2.1655	0.0038
3	0	CU3	2.2008	2.1987	-0.0021
11	30	Unbiased-30krad	2.2312	2.2275	-0.0037
12	30	Unbiased-30krad	2.3548	2.3291	-0.0257
13	30	Unbiased-30krad	2.2067	2.1896	-0.0171
14	30	Unbiased-30krad	2.226	2.2149	-0.0111
15	30	Unbiased-30krad	2.0831	2.0734	-0.0097
16	35	Biased-30krad	2.2687	2.1947	-0.074
17	35	Biased-30krad	2.2027	2.1185	-0.0842
18	35	Biased-30krad	2.3397	2.2508	-0.0889
19	35	Biased-30krad	2.2398	2.1643	-0.0755
20	35	Biased-30krad	2.0914	2.0177	-0.0737
30	50	Unbiased-50krad	2.2604	2.2429	-0.0175
31	50	Unbiased-50krad	2.2162	2.2082	-0.008
32	50	Unbiased-50krad	2.1763	2.1639	-0.0124
33	50	Unbiased-50krad	2.1151	2.0967	-0.0184
34	50	Unbiased-50krad	2.1095	2.0928	-0.0167
40	55	Biased-50krad	2.275	2.1347	-0.1403
41	55	Biased-50krad	2.2497	2.1212	-0.1285
42	55	Biased-50krad	2.2825	2.1505	-0.132
43	55	Biased-50krad	2.0783	1.9604	-0.1179
44	55	Biased-50krad	2.1684	2.0517	-0.1167
45	100	Unbiased-100krad	2.2043	2.1789	-0.0254
46	100	Unbiased-100krad	2.2047	2.1892	-0.0155
47	100	Unbiased-100krad	2.1735	2.1627	-0.0108
48	100	Unbiased-100krad	2.23	2.2054	-0.0246
49	100	Unbiased-100krad	2.1459	2.1544	0.0085
50	105	Biased-100krad	2.2635	2.0722	-0.1913
51	105	Biased-100krad	2.1392	1.9643	-0.1749
52	105	Biased-100krad	2.2252	2.0331	-0.1921
53	105	Biased-100krad	2.1064	1.9375	-0.1689
54	105	Biased-100krad	2.215	2.0169	-0.1981

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1494	2.1706	2.2008	0.026839	2.1445	2.1696	2.1987	0.027328	-0.0049	-0.0010667	0.0038	0.0044411
30	2.0831	2.2204	2.3548	0.096502	2.0734	2.2069	2.3291	0.091573	-0.0257	-0.01346	-0.0037	0.0083371
35	2.0914	2.2285	2.3397	0.091612	2.0177	2.1492	2.2508	0.087829	-0.0889	-0.07926	-0.0737	0.006893
50	2.1095	2.1755	2.2604	0.064941	2.0928	2.1609	2.2429	0.066576	-0.0184	-0.0146	-0.008	0.0043491
55	2.0783	2.2108	2.2825	0.08679	1.9604	2.0837	2.1505	0.078575	-0.1403	-0.12708	-0.1167	0.0099122
100	2.1459	2.1917	2.23	0.032494	2.1544	2.1781	2.2054	0.020421	-0.0254	-0.01356	0.0085	0.013785
105	2.1064	2.1899	2.2635	0.064876	1.9375	2.0048	2.0722	0.05399	-0.1981	-0.18506	-0.1689	0.012479

Device Test: 30.1 _PWRGD|VOL/PWRGD1/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW





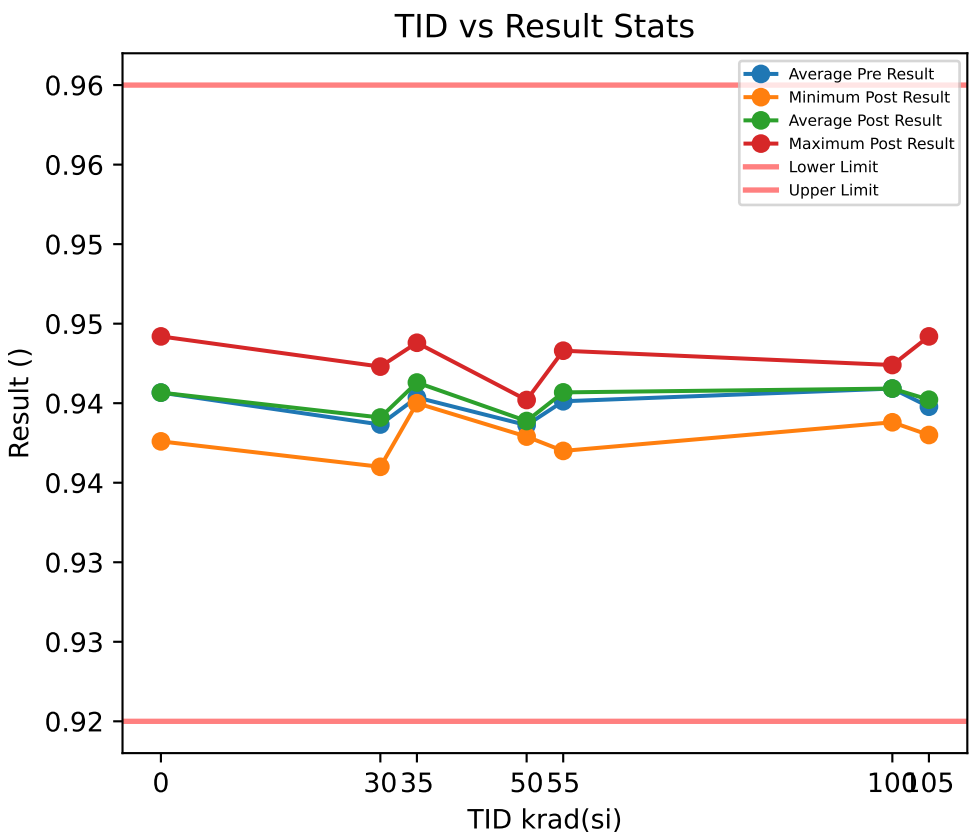
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

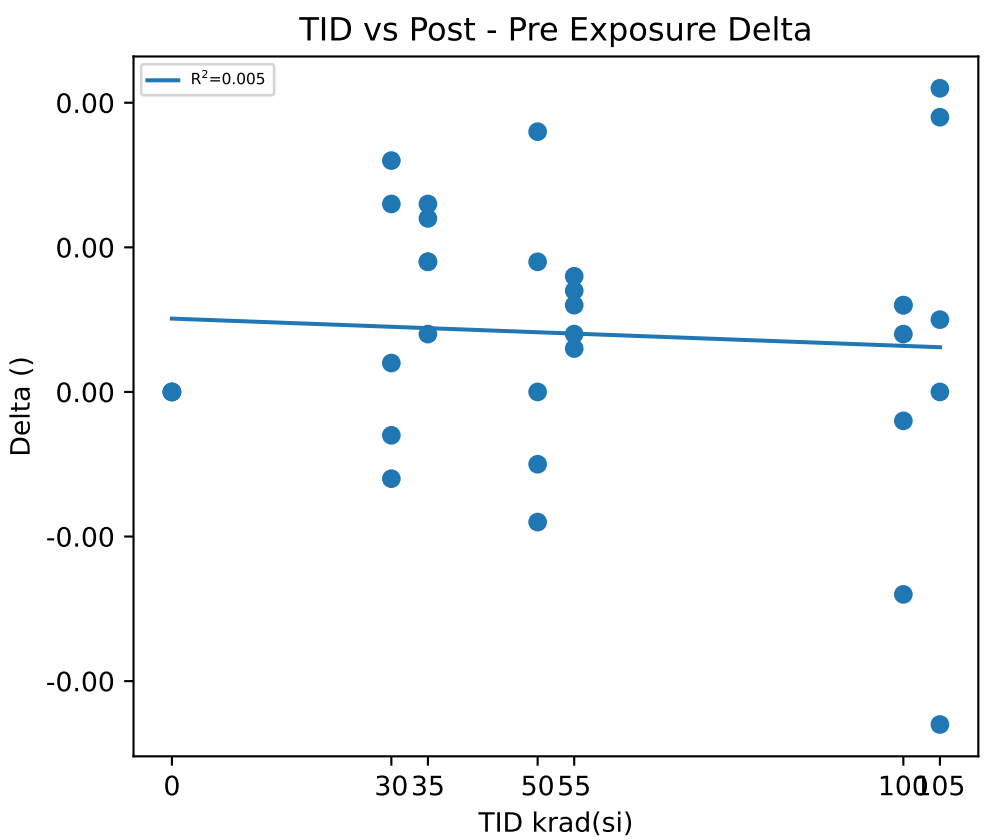
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	317.04	317.57	0.5297
2	0	CU2	314.52	315.02	0.5078
3	0	CU3	316.79	317.21	0.4173
11	30	Unbiased-30krad	313.45	313.62	0.1768
12	30	Unbiased-30krad	316.37	316.52	0.1518
13	30	Unbiased-30krad	313.49	313.64	0.1456
14	30	Unbiased-30krad	316.07	316.25	0.1769
15	30	Unbiased-30krad	317.93	318.11	0.1768
16	35	Biased-30krad	316.73	317.04	0.308
17	35	Biased-30krad	315.45	315.63	0.1831
18	35	Biased-30krad	317.33	317.48	0.1487
19	35	Biased-30krad	313.6	313.78	0.1799
20	35	Biased-30krad	313.88	313.93	0.0519
30	50	Unbiased-50krad	315.73	315.71	-0.0262
31	50	Unbiased-50krad	312.3	312.38	0.0863
32	50	Unbiased-50krad	317.69	317.6	-0.0824
33	50	Unbiased-50krad	316	315.89	-0.1105
34	50	Unbiased-50krad	318.9	318.69	-0.2042
40	55	Biased-50krad	313.66	313.55	-0.1073
41	55	Biased-50krad	315.19	315.26	0.0676
42	55	Biased-50krad	318.16	318.2	0.0331
43	55	Biased-50krad	316.49	316.48	-0.0168
44	55	Biased-50krad	314.48	314.32	-0.1573
45	100	Unbiased-100krad	314.25	313.9	-0.354
46	100	Unbiased-100krad	315.28	314.96	-0.3134
47	100	Unbiased-100krad	314.25	313.77	-0.4727
48	100	Unbiased-100krad	314.3	313.87	-0.429
49	100	Unbiased-100krad	317.66	317.22	-0.4415
50	105	Biased-100krad	317.06	317.02	-0.0386
51	105	Biased-100krad	313.88	313.82	-0.0668
52	105	Biased-100krad	316.13	316.2	0.0644
53	105	Biased-100krad	314.93	314.89	-0.0355
54	105	Biased-100krad	317.51	317.33	-0.1792

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	314.52	316.12	317.04	1.3913	315.02	316.6	317.57	1.3779	0.4173	0.48493	0.5297	0.059587
30	313.45	315.46	317.93	1.9525	313.62	315.63	318.11	1.9575	0.1456	0.16558	0.1769	0.015564
35	313.6	315.4	317.33	1.6627	313.78	315.57	317.48	1.7104	0.0519	0.17432	0.308	0.091681
50	312.3	316.12	318.9	2.4977	312.38	316.06	318.69	2.3977	-0.2042	-0.0674	0.0863	0.10738
55	313.66	315.6	318.16	1.7724	313.55	315.56	318.2	1.834	-0.1573	-0.03614	0.0676	0.094437
100	314.25	315.15	317.66	1.4722	313.77	314.74	317.22	1.4662	-0.4727	-0.40212	-0.3134	0.066033
105	313.88	315.9	317.51	1.5003	313.82	315.85	317.33	1.478	-0.1792	-0.05114	0.0644	0.087172

Device Test: 30.10 _PWRGD|RisingGood/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





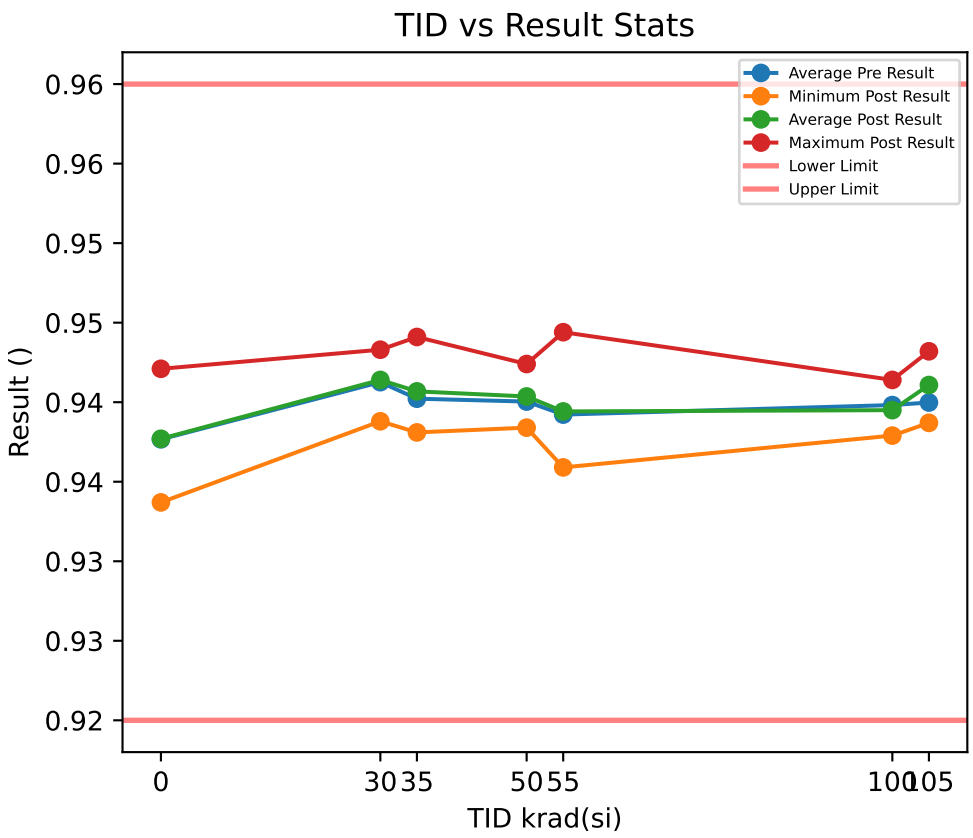
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

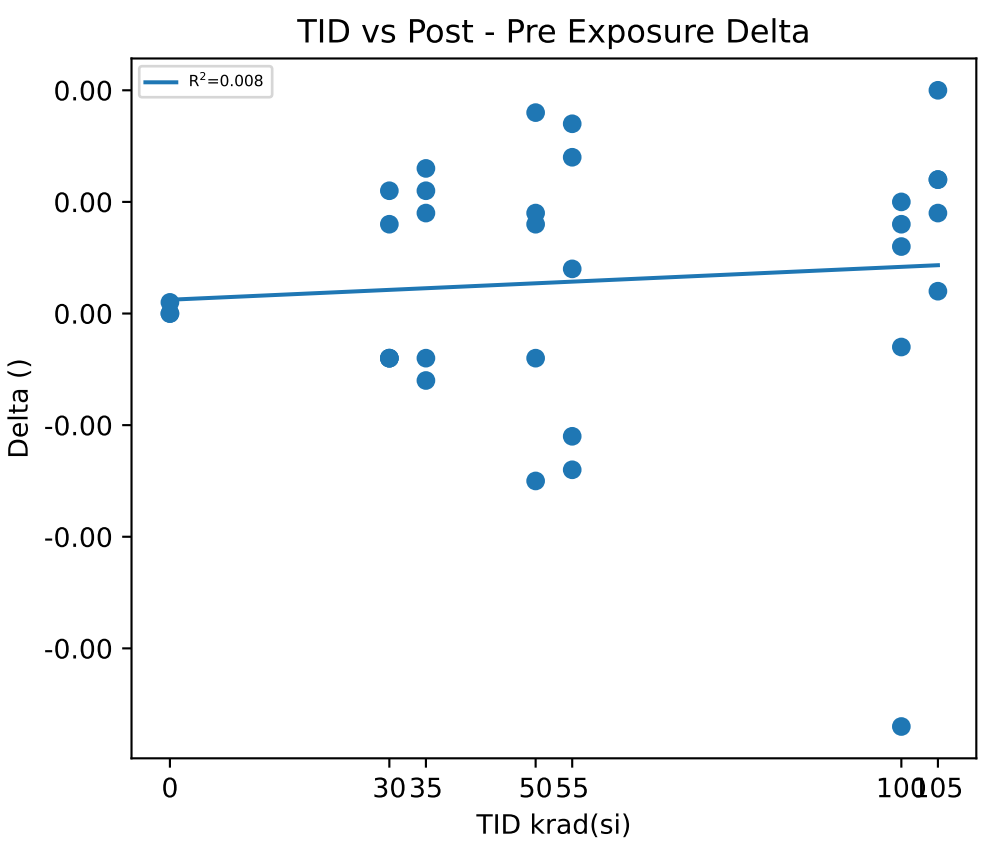
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9442	0.9442	0
2	0	CU2	0.9402	0.9402	0
3	0	CU3	0.9376	0.9376	0
11	30	Unbiased-30krad	0.9363	0.936	-0.0003
12	30	Unbiased-30krad	0.9406	0.94	-0.0006
13	30	Unbiased-30krad	0.941	0.9423	0.0013
14	30	Unbiased-30krad	0.938	0.9382	0.0002
15	30	Unbiased-30krad	0.9374	0.939	0.0016
16	35	Biased-30krad	0.9397	0.9406	0.0009
17	35	Biased-30krad	0.9391	0.94	0.0009
18	35	Biased-30krad	0.9394	0.9406	0.0012
19	35	Biased-30krad	0.9425	0.9438	0.0013
20	35	Biased-30krad	0.9411	0.9415	0.0004
30	50	Unbiased-50krad	0.9384	0.9384	0
31	50	Unbiased-50krad	0.9392	0.9383	-0.0009
32	50	Unbiased-50krad	0.9378	0.9396	0.0018
33	50	Unbiased-50krad	0.9384	0.9379	-0.0005
34	50	Unbiased-50krad	0.9393	0.9402	0.0009
40	55	Biased-50krad	0.9427	0.9433	0.0006
41	55	Biased-50krad	0.9423	0.9427	0.0004
42	55	Biased-50krad	0.9362	0.937	0.0008
43	55	Biased-50krad	0.9392	0.9395	0.0003
44	55	Biased-50krad	0.9402	0.9409	0.0007
45	100	Unbiased-100krad	0.9438	0.9424	-0.0014
46	100	Unbiased-100krad	0.9382	0.9388	0.0006
47	100	Unbiased-100krad	0.9403	0.9409	0.0006
48	100	Unbiased-100krad	0.9422	0.942	-0.0002
49	100	Unbiased-100krad	0.9401	0.9405	0.0004
50	105	Biased-100krad	0.938	0.938	0
51	105	Biased-100krad	0.9386	0.9405	0.0019
52	105	Biased-100krad	0.9381	0.9402	0.0021
53	105	Biased-100krad	0.9405	0.9382	-0.0023
54	105	Biased-100krad	0.9437	0.9442	0.0005

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9376	0.94067	0.9442	0.0033247	0.9376	0.94067	0.9442	0.0033247	0	0	0	0
30	0.9363	0.93866	0.941	0.0020513	0.936	0.9391	0.9423	0.0023173	-0.0006	0.00044	0.0016	0.00097108
35	0.9391	0.94036	0.9425	0.0014206	0.94	0.9413	0.9438	0.0014967	0.0004	0.00094	0.0013	0.00035071
50	0.9378	0.93862	0.9393	0.0006261	0.9379	0.93888	0.9402	0.00097314	-0.0009	0.00026	0.0018	0.0010922
55	0.9362	0.94012	0.9427	0.0026281	0.937	0.94068	0.9433	0.002546	0.0003	0.00056	0.0008	0.00020736
100	0.9382	0.94092	0.9438	0.0021441	0.9388	0.94092	0.9424	0.0014167	-0.0014	-4.4409e-17	0.0006	0.00084853
105	0.938	0.93978	0.9437	0.0024118	0.938	0.94022	0.9442	0.0024964	-0.0023	0.00044	0.0021	0.0017743

Device Test: 30.11 _PWRGD|RisingGood/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





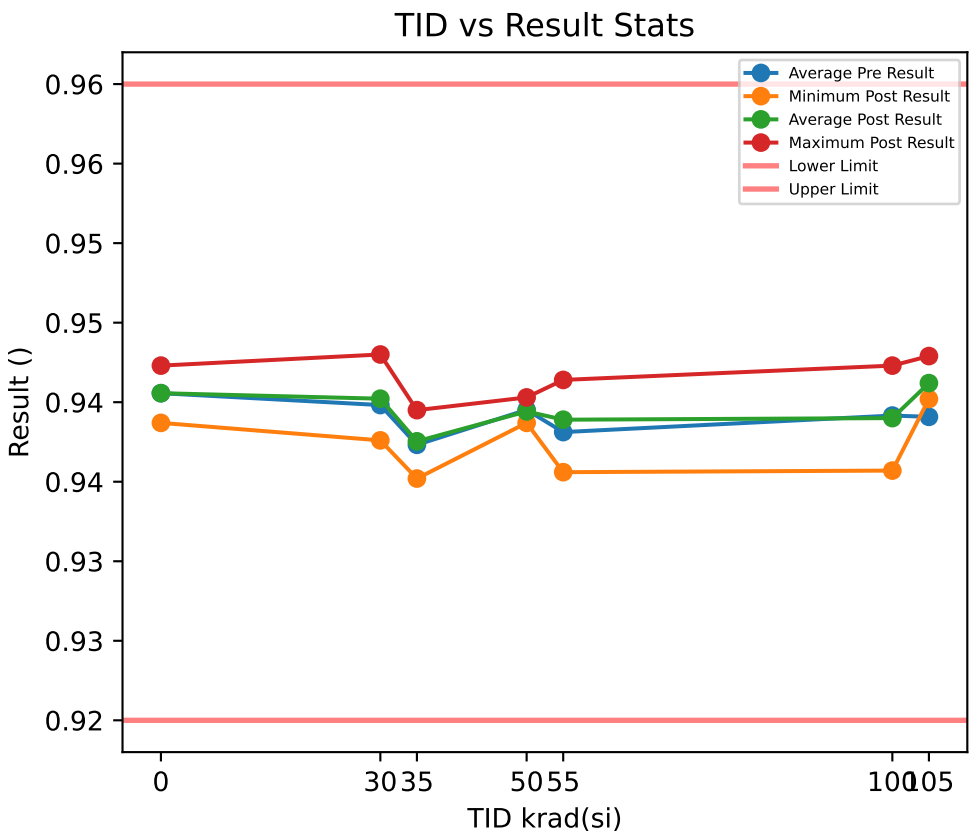
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

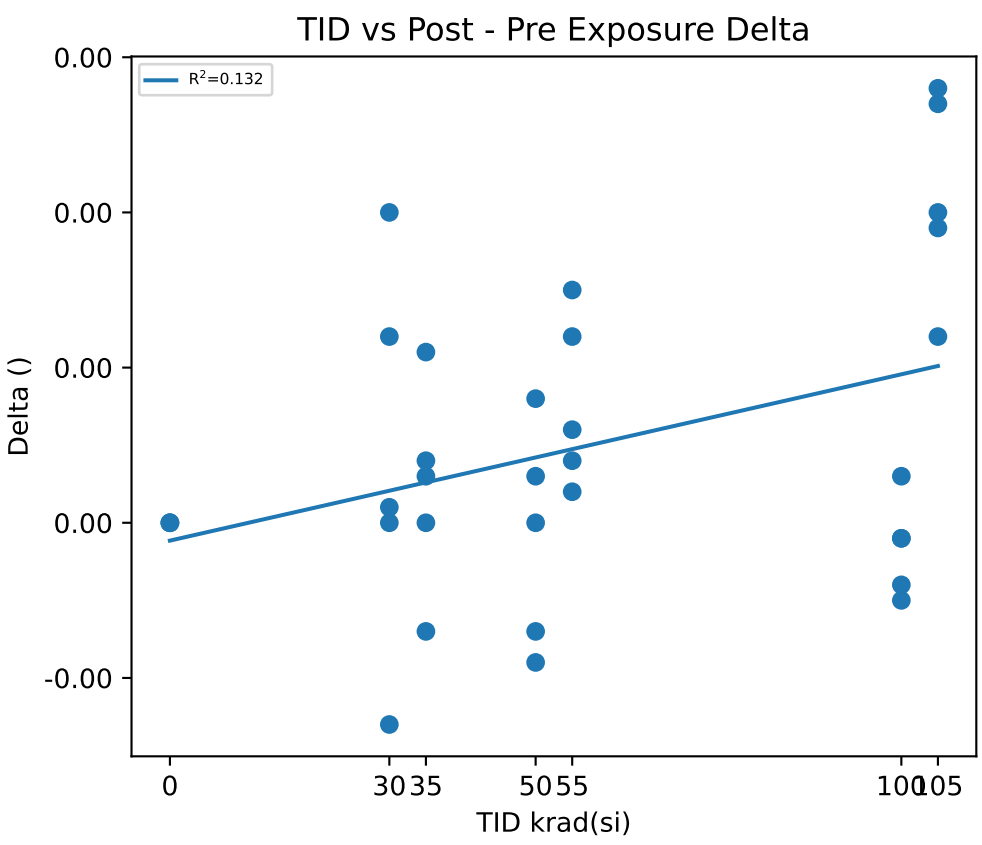
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9421	0.9421	0
2	0	CU2	0.9336	0.9337	0.0001
3	0	CU3	0.9373	0.9373	0
11	30	Unbiased-30krad	0.9437	0.9433	-0.0004
12	30	Unbiased-30krad	0.9411	0.9422	0.0011
13	30	Unbiased-30krad	0.9433	0.9429	-0.0004
14	30	Unbiased-30krad	0.9392	0.9388	-0.0004
15	30	Unbiased-30krad	0.939	0.9398	0.0008
16	35	Biased-30krad	0.9405	0.9414	0.0009
17	35	Biased-30krad	0.9407	0.9401	-0.0006
18	35	Biased-30krad	0.9401	0.9397	-0.0004
19	35	Biased-30krad	0.9428	0.9441	0.0013
20	35	Biased-30krad	0.937	0.9381	0.0011
30	50	Unbiased-50krad	0.9375	0.9384	0.0009
31	50	Unbiased-50krad	0.9382	0.939	0.0008
32	50	Unbiased-50krad	0.9403	0.9421	0.0018
33	50	Unbiased-50krad	0.9403	0.9399	-0.0004
34	50	Unbiased-50krad	0.9439	0.9424	-0.0015
40	55	Biased-50krad	0.9407	0.9393	-0.0014
41	55	Biased-50krad	0.9388	0.9392	0.0004
42	55	Biased-50krad	0.9427	0.9444	0.0017
43	55	Biased-50krad	0.9369	0.9383	0.0014
44	55	Biased-50krad	0.937	0.9359	-0.0011
45	100	Unbiased-100krad	0.9371	0.9381	0.001
46	100	Unbiased-100krad	0.9391	0.9397	0.0006
47	100	Unbiased-100krad	0.9382	0.9379	-0.0003
48	100	Unbiased-100krad	0.9406	0.9414	0.0008
49	100	Unbiased-100krad	0.9441	0.9404	-0.0037
50	105	Biased-100krad	0.9395	0.9404	0.0009
51	105	Biased-100krad	0.942	0.9432	0.0012
52	105	Biased-100krad	0.939	0.941	0.002
53	105	Biased-100krad	0.9385	0.9387	0.0002
54	105	Biased-100krad	0.9409	0.9421	0.0012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9336	0.93767	0.9421	0.0042618	0.9337	0.9377	0.9421	0.0042143	0	3.3333e-05	0.0001	5.7735e-05
30	0.939	0.94126	0.9437	0.0022075	0.9388	0.9414	0.9433	0.0019887	-0.0004	0.00014	0.0011	0.00074699
35	0.937	0.94022	0.9428	0.0020825	0.9381	0.94068	0.9441	0.0022454	-0.0006	0.00046	0.0013	0.00089051
50	0.9375	0.94004	0.9439	0.0024936	0.9384	0.94036	0.9424	0.0018091	-0.0015	0.00032	0.0018	0.0012834
55	0.9369	0.93922	0.9427	0.0024894	0.9359	0.93942	0.9444	0.0031027	-0.0014	0.0002	0.0017	0.0014124
100	0.9371	0.93982	0.9441	0.0027142	0.9379	0.9395	0.9414	0.0014983	-0.0037	-0.00032	0.001	0.0019537
105	0.9385	0.93998	0.942	0.0014412	0.9387	0.94108	0.9432	0.0017079	0.0002	0.0011	0.002	0.00064807

Device Test: 30.12 _PWRGD|RisingGood/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





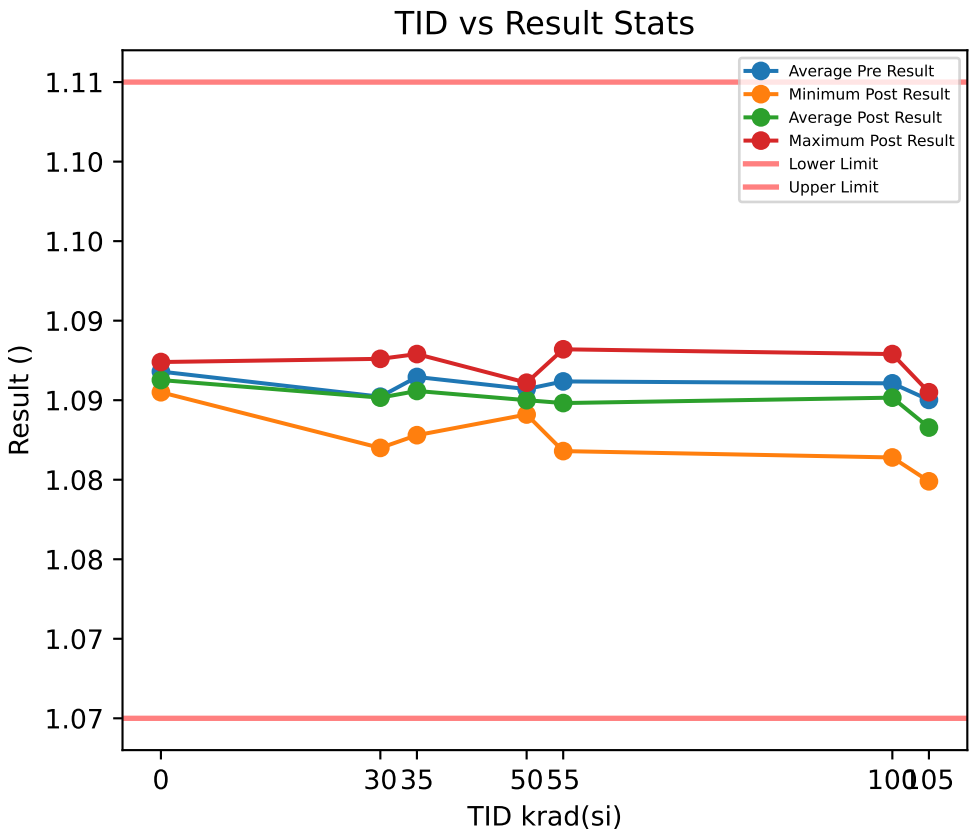
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

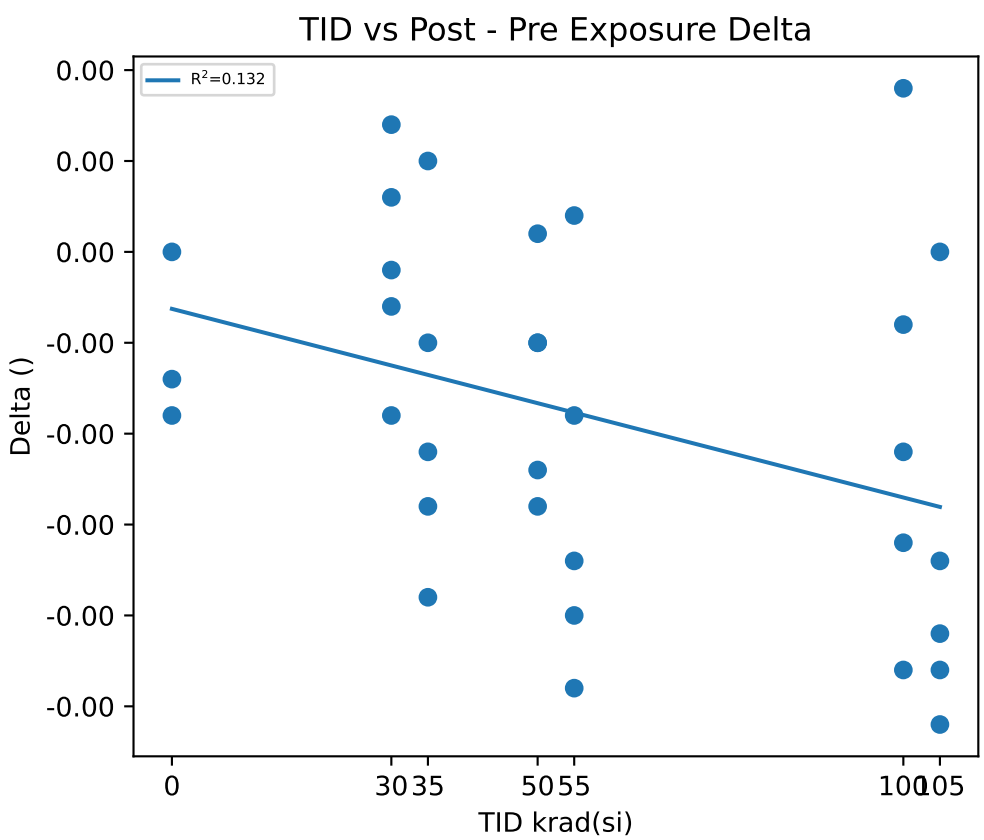
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9423	0.9423	0
2	0	CU2	0.9387	0.9387	0
3	0	CU3	0.9407	0.9407	0
11	30	Unbiased-30krad	0.9417	0.9404	-0.0013
12	30	Unbiased-30krad	0.9375	0.9376	0.0001
13	30	Unbiased-30krad	0.9378	0.939	0.0012
14	30	Unbiased-30krad	0.941	0.943	0.002
15	30	Unbiased-30krad	0.9411	0.9411	0
16	35	Biased-30krad	0.9352	0.9352	0
17	35	Biased-30krad	0.9379	0.9372	-0.0007
18	35	Biased-30krad	0.9375	0.9378	0.0003
19	35	Biased-30krad	0.9391	0.9395	0.0004
20	35	Biased-30krad	0.9369	0.938	0.0011
30	50	Unbiased-50krad	0.9396	0.9396	0
31	50	Unbiased-50krad	0.9379	0.9387	0.0008
32	50	Unbiased-50krad	0.9403	0.9394	-0.0009
33	50	Unbiased-50krad	0.9388	0.9391	0.0003
34	50	Unbiased-50krad	0.941	0.9403	-0.0007
40	55	Biased-50krad	0.9409	0.9411	0.0002
41	55	Biased-50krad	0.9402	0.9414	0.0012
42	55	Biased-50krad	0.9376	0.9391	0.0015
43	55	Biased-50krad	0.9369	0.9373	0.0004
44	55	Biased-50krad	0.935	0.9356	0.0006
45	100	Unbiased-100krad	0.9428	0.9423	-0.0005
46	100	Unbiased-100krad	0.9408	0.9407	-0.0001
47	100	Unbiased-100krad	0.939	0.9386	-0.0004
48	100	Unbiased-100krad	0.9358	0.9357	-0.0001
49	100	Unbiased-100krad	0.9374	0.9377	0.0003
50	105	Biased-100krad	0.9377	0.9404	0.0027
51	105	Biased-100krad	0.939	0.9402	0.0012
52	105	Biased-100krad	0.9394	0.9414	0.002
53	105	Biased-100krad	0.941	0.9429	0.0019
54	105	Biased-100krad	0.9383	0.9411	0.0028

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9387	0.94057	0.9423	0.0018037	0.9387	0.94057	0.9423	0.0018037	0	0	0	0
30	0.9375	0.93982	0.9417	0.0020017	0.9376	0.94022	0.943	0.0020548	-0.0013	0.0004	0.002	0.001259
35	0.9352	0.93732	0.9391	0.0014325	0.9352	0.93754	0.9395	0.0015582	-0.0007	0.00022	0.0011	0.00065345
50	0.9379	0.93952	0.941	0.0012194	0.9387	0.93942	0.9403	0.00059749	-0.0009	-0.0001	0.0008	0.00070356
55	0.935	0.93812	0.9409	0.0024263	0.9356	0.9389	0.9414	0.0024789	0.0002	0.00078	0.0015	0.00054955
100	0.9358	0.93916	0.9428	0.0027546	0.9357	0.939	0.9423	0.0025749	-0.0005	-0.00016	0.0003	0.00031305
105	0.9377	0.93908	0.941	0.0012558	0.9402	0.9412	0.9429	0.00107	0.0012	0.00212	0.0028	0.00065345

Device Test: 30.13 _PWRGD|RisingFault/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





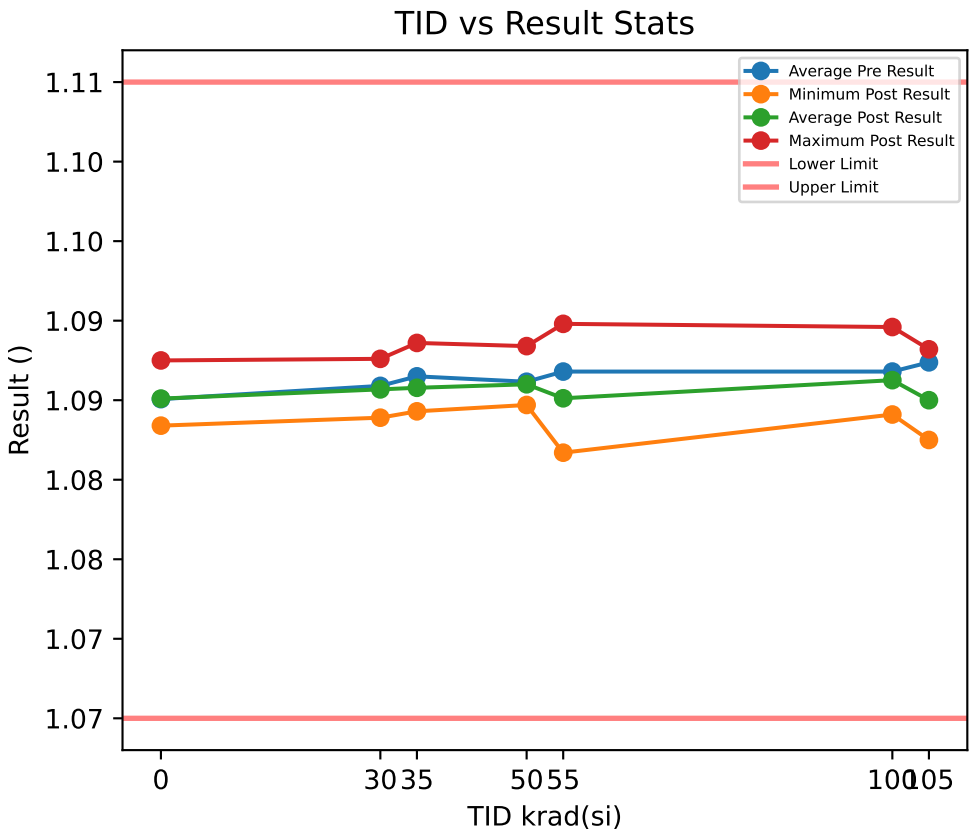
Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

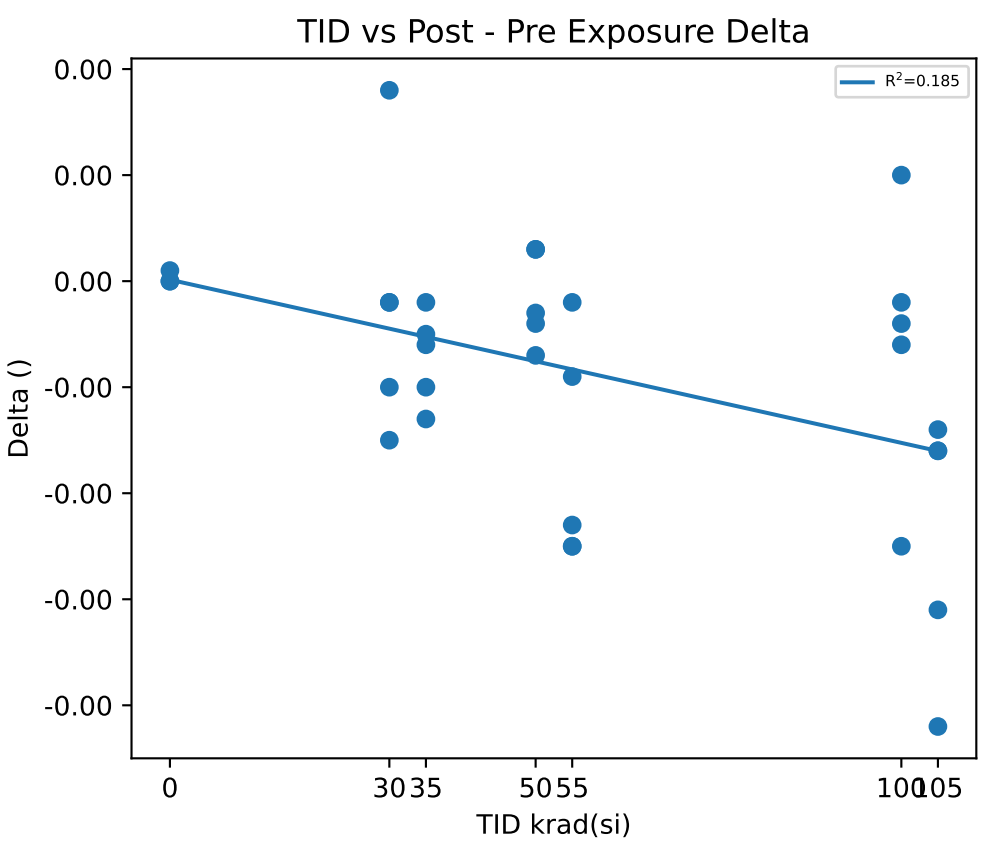
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0905	1.0905	0
2	0	CU2	1.0916	1.0909	-0.0007
3	0	CU3	1.0933	1.0924	-0.0009
11	30	Unbiased-30krad	1.0914	1.0921	0.0007
12	30	Unbiased-30krad	1.0867	1.087	0.0003
13	30	Unbiased-30krad	1.089	1.0887	-0.0003
14	30	Unbiased-30krad	1.0927	1.0926	-0.0001
15	30	Unbiased-30krad	1.0913	1.0904	-0.0009
16	35	Biased-30krad	1.0892	1.0878	-0.0014
17	35	Biased-30krad	1.0906	1.0901	-0.0005
18	35	Biased-30krad	1.094	1.0929	-0.0011
19	35	Biased-30krad	1.0915	1.0896	-0.0019
20	35	Biased-30krad	1.092	1.0925	0.0005
30	50	Unbiased-50krad	1.089	1.0891	0.0001
31	50	Unbiased-50krad	1.0898	1.0893	-0.0005
32	50	Unbiased-50krad	1.0913	1.0899	-0.0014
33	50	Unbiased-50krad	1.0918	1.0906	-0.0012
34	50	Unbiased-50krad	1.0916	1.0911	-0.0005
40	55	Biased-50krad	1.0907	1.0883	-0.0024
41	55	Biased-50krad	1.0952	1.0932	-0.002
42	55	Biased-50krad	1.0905	1.0907	0.0002
43	55	Biased-50krad	1.091	1.0901	-0.0009
44	55	Biased-50krad	1.0885	1.0868	-0.0017
45	100	Unbiased-100krad	1.0938	1.0922	-0.0016
46	100	Unbiased-100krad	1.0904	1.0881	-0.0023
47	100	Unbiased-100krad	1.0875	1.0864	-0.0011
48	100	Unbiased-100krad	1.0933	1.0929	-0.0004
49	100	Unbiased-100krad	1.0903	1.0912	0.0009
50	105	Biased-100krad	1.0901	1.088	-0.0021
51	105	Biased-100krad	1.0931	1.0905	-0.0026
52	105	Biased-100krad	1.0872	1.0849	-0.0023
53	105	Biased-100krad	1.0899	1.0899	0
54	105	Biased-100krad	1.0898	1.0881	-0.0017

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0905	1.0918	1.0933	0.0014107	1.0905	1.0913	1.0924	0.0010017	-0.0009	-0.00053333	0	0.00047258
30	1.0867	1.0902	1.0927	0.0023763	1.087	1.0902	1.0926	0.0023394	-0.0009	-6e-05	0.0007	0.00060663
35	1.0892	1.0915	1.094	0.0017743	1.0878	1.0906	1.0929	0.0021206	-0.0019	-0.00088	0.0005	0.00092304
50	1.089	1.0907	1.0918	0.0012329	1.0891	1.09	1.0911	0.00084853	-0.0014	-0.0007	0.0001	0.00060415
55	1.0885	1.0912	1.0952	0.002453	1.0868	1.0898	1.0932	0.0024345	-0.0024	-0.00136	0.0002	0.001031
100	1.0875	1.0911	1.0938	0.0025599	1.0864	1.0902	1.0929	0.0027898	-0.0023	-0.0009	0.0009	0.0012227
105	1.0872	1.09	1.0931	0.0020921	1.0849	1.0883	1.0905	0.0021845	-0.0026	-0.00174	0	0.0010262

Device Test: 30.14 _PWRGD|RisingFault/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





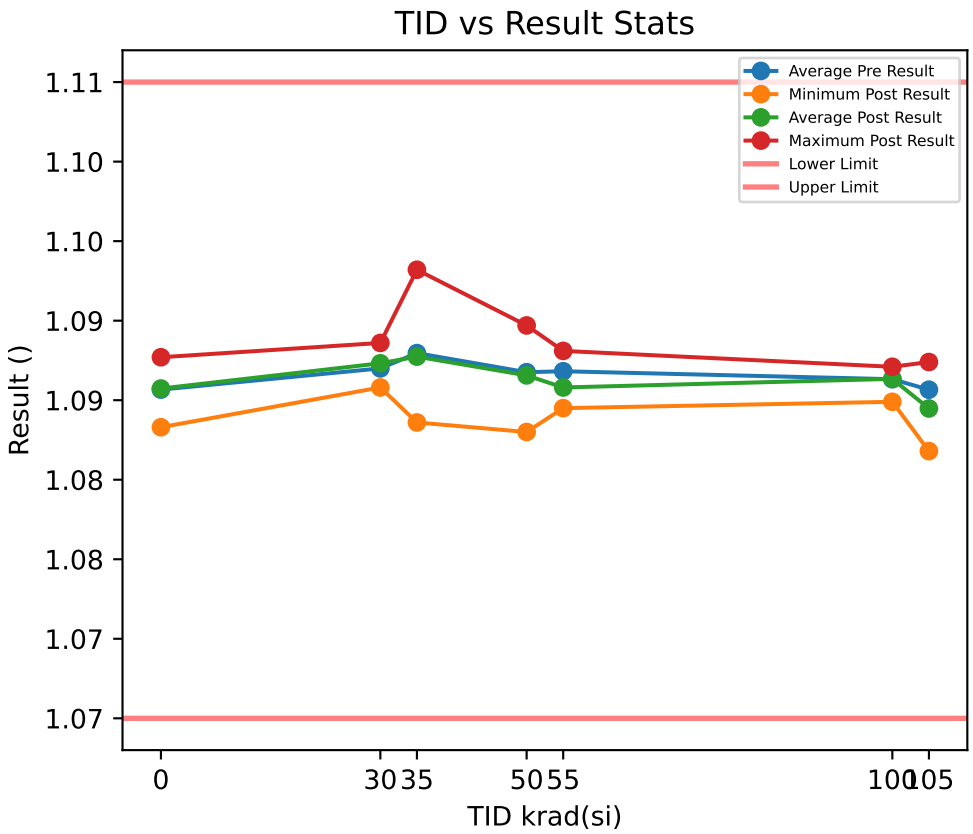
Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

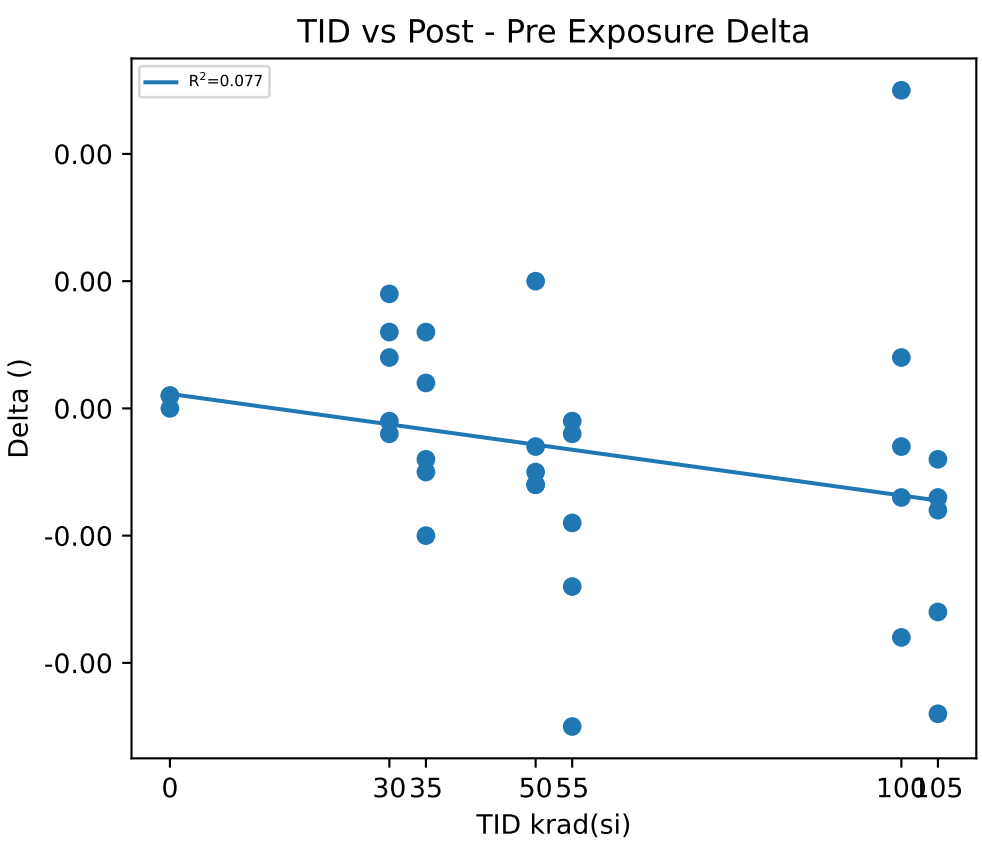
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0925	1.0925	0
2	0	CU2	1.0883	1.0884	0.0001
3	0	CU3	1.0894	1.0894	0
11	30	Unbiased-30krad	1.0907	1.0905	-0.0002
12	30	Unbiased-30krad	1.0925	1.091	-0.0015
13	30	Unbiased-30krad	1.0914	1.0904	-0.001
14	30	Unbiased-30krad	1.0891	1.0889	-0.0002
15	30	Unbiased-30krad	1.0908	1.0926	0.0018
16	35	Biased-30krad	1.0917	1.0911	-0.0006
17	35	Biased-30krad	1.0902	1.0897	-0.0005
18	35	Biased-30krad	1.0895	1.0893	-0.0002
19	35	Biased-30krad	1.0912	1.0902	-0.001
20	35	Biased-30krad	1.0949	1.0936	-0.0013
30	50	Unbiased-50krad	1.091	1.0903	-0.0007
31	50	Unbiased-50krad	1.0894	1.0897	0.0003
32	50	Unbiased-50krad	1.0904	1.09	-0.0004
33	50	Unbiased-50krad	1.0937	1.0934	-0.0003
34	50	Unbiased-50krad	1.0913	1.0916	0.0003
40	55	Biased-50krad	1.0927	1.0902	-0.0025
41	55	Biased-50krad	1.0876	1.0867	-0.0009
42	55	Biased-50krad	1.0922	1.0899	-0.0023
43	55	Biased-50krad	1.095	1.0948	-0.0002
44	55	Biased-50krad	1.0915	1.089	-0.0025
45	100	Unbiased-100krad	1.0934	1.0909	-0.0025
46	100	Unbiased-100krad	1.0936	1.0946	0.001
47	100	Unbiased-100krad	1.0915	1.0913	-0.0002
48	100	Unbiased-100krad	1.0908	1.0904	-0.0004
49	100	Unbiased-100krad	1.0897	1.0891	-0.0006
50	105	Biased-100krad	1.0946	1.0932	-0.0014
51	105	Biased-100krad	1.0906	1.0875	-0.0031
52	105	Biased-100krad	1.0907	1.0891	-0.0016
53	105	Biased-100krad	1.0933	1.0891	-0.0042
54	105	Biased-100krad	1.0927	1.0911	-0.0016

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0883	1.0901	1.0925	0.0021779	1.0884	1.0901	1.0925	0.0021378	0	3.3333e-05	0.0001	5.7735e-05
30	1.0891	1.0909	1.0925	0.0012349	1.0889	1.0907	1.0926	0.0013293	-0.0015	-0.00022	0.0018	0.0012578
35	1.0895	1.0915	1.0949	0.0020845	1.0893	1.0908	1.0936	0.0017138	-0.0013	-0.00072	-0.0002	0.00043243
50	1.0894	1.0912	1.0937	0.0015947	1.0897	1.091	1.0934	0.0015248	-0.0007	-0.00016	0.0003	0.00044497
55	1.0876	1.0918	1.095	0.0026898	1.0867	1.0901	1.0948	0.0029541	-0.0025	-0.00168	-0.0002	0.001064
100	1.0897	1.0918	1.0936	0.0016808	1.0891	1.0913	1.0946	0.0020428	-0.0025	-0.00054	0.001	0.0012602
105	1.0906	1.0924	1.0946	0.0017225	1.0875	1.09	1.0932	0.0021977	-0.0042	-0.00238	-0.0014	0.0012256

Device Test: 30.15 _PWRGD|RisingFault/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





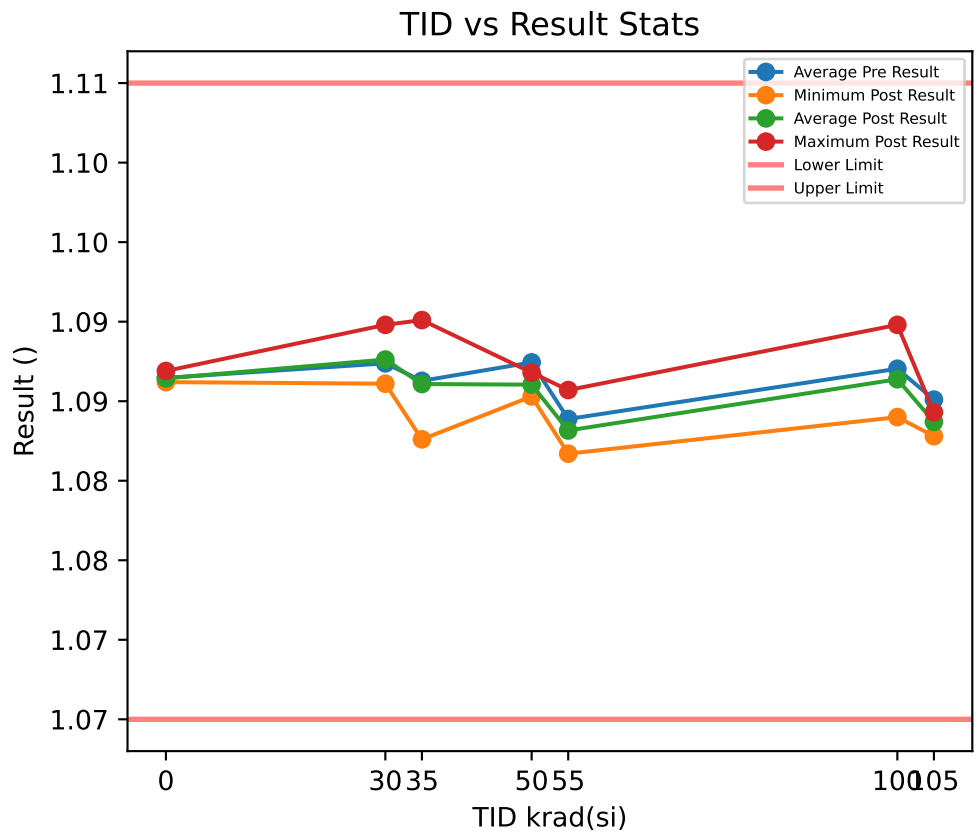
Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

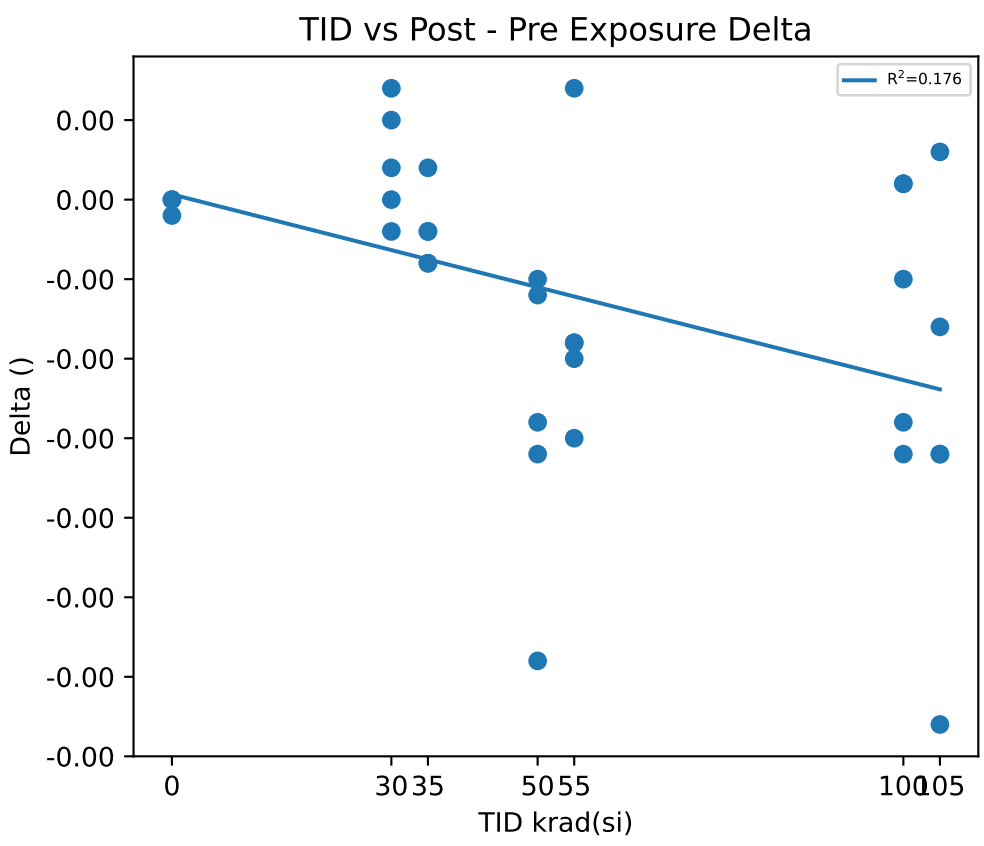
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0926	1.0927	0.0001
2	0	CU2	1.0911	1.0912	0.0001
3	0	CU3	1.0883	1.0883	0
11	30	Unbiased-30krad	1.0937	1.0936	-0.0001
12	30	Unbiased-30krad	1.0932	1.0936	0.0004
13	30	Unbiased-30krad	1.0919	1.0925	0.0006
14	30	Unbiased-30krad	1.091	1.0908	-0.0002
15	30	Unbiased-30krad	1.0902	1.0911	0.0009
16	35	Biased-30krad	1.0909	1.0911	0.0002
17	35	Biased-30krad	1.0963	1.0958	-0.0005
18	35	Biased-30krad	1.088	1.0886	0.0006
19	35	Biased-30krad	1.0992	1.0982	-0.001
20	35	Biased-30krad	1.0904	1.09	-0.0004
30	50	Unbiased-50krad	1.0937	1.0947	0.001
31	50	Unbiased-50krad	1.0929	1.0924	-0.0005
32	50	Unbiased-50krad	1.0922	1.0916	-0.0006
33	50	Unbiased-50krad	1.0914	1.0911	-0.0003
34	50	Unbiased-50krad	1.0886	1.088	-0.0006
40	55	Biased-50krad	1.0956	1.0931	-0.0025
41	55	Biased-50krad	1.0906	1.0904	-0.0002
42	55	Biased-50krad	1.0909	1.0895	-0.0014
43	55	Biased-50krad	1.0907	1.0898	-0.0009
44	55	Biased-50krad	1.0913	1.0912	-0.0001
45	100	Unbiased-100krad	1.0883	1.0908	0.0025
46	100	Unbiased-100krad	1.0928	1.0921	-0.0007
47	100	Unbiased-100krad	1.0902	1.0899	-0.0003
48	100	Unbiased-100krad	1.0917	1.0921	0.0004
49	100	Unbiased-100krad	1.0936	1.0918	-0.0018
50	105	Biased-100krad	1.0881	1.0877	-0.0004
51	105	Biased-100krad	1.0916	1.0909	-0.0007
52	105	Biased-100krad	1.094	1.0924	-0.0016
53	105	Biased-100krad	1.0892	1.0868	-0.0024
54	105	Biased-100krad	1.0904	1.0896	-0.0008

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0883	1.0907	1.0926	0.0021825	1.0883	1.0907	1.0927	0.0022368	0	6.6667e-05	0.0001	5.7735e-05
30	1.0902	1.092	1.0937	0.0014646	1.0908	1.0923	1.0936	0.001333	-0.0002	0.00032	0.0009	0.00046583
35	1.088	1.093	1.0992	0.0046231	1.0886	1.0927	1.0982	0.0040777	-0.001	-0.00022	0.0006	0.0006261
50	1.0886	1.0918	1.0937	0.0019604	1.088	1.0916	1.0947	0.0024214	-0.0006	-0.0002	0.001	0.00068191
55	1.0906	1.0918	1.0956	0.00213	1.0895	1.0908	1.0931	0.0014405	-0.0025	-0.00102	-0.0001	0.00098336
100	1.0883	1.0913	1.0936	0.0021159	1.0899	1.0913	1.0921	0.00096592	-0.0018	2e-05	0.0025	0.0015991
105	1.0881	1.0907	1.094	0.0022799	1.0868	1.0895	1.0924	0.0022863	-0.0024	-0.00118	-0.0004	0.00081363

Device Test: 30.16 _PWRGD|RisingFault/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

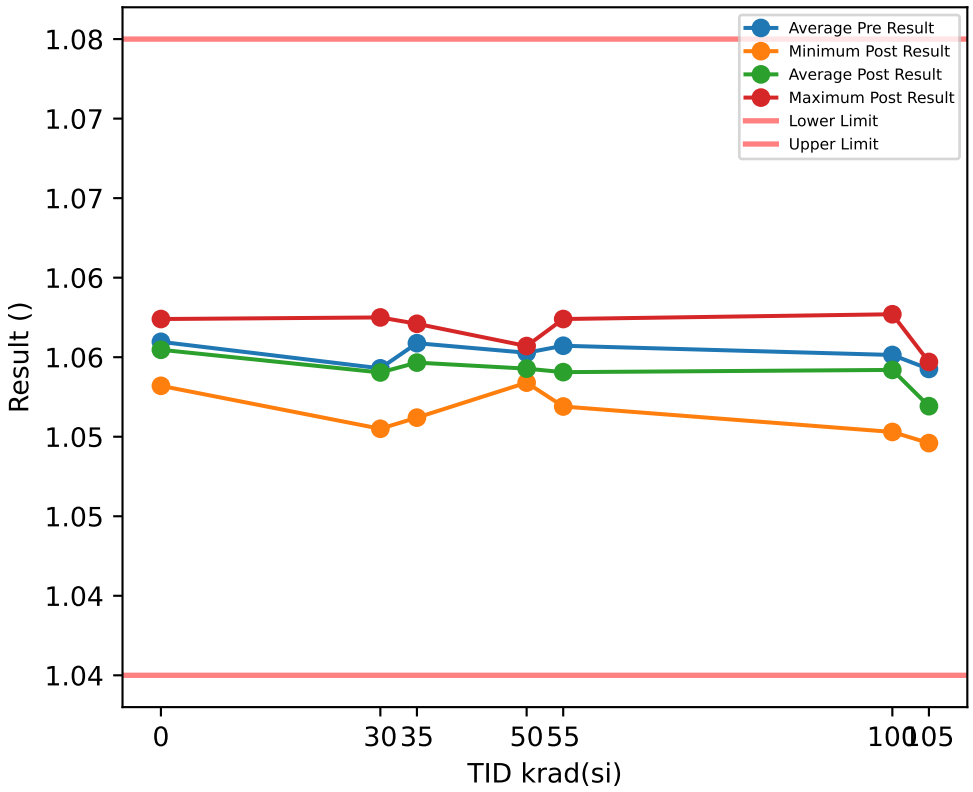
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0912	1.0912	0
2	0	CU2	1.0912	1.0912	0
3	0	CU3	1.092	1.0919	-0.0001
11	30	Unbiased-30krad	1.0913	1.0911	-0.0002
12	30	Unbiased-30krad	1.0927	1.0929	0.0002
13	30	Unbiased-30krad	1.0913	1.0918	0.0005
14	30	Unbiased-30krad	1.0941	1.0948	0.0007
15	30	Unbiased-30krad	1.0925	1.0925	0
16	35	Biased-30krad	1.0907	1.0909	0.0002
17	35	Biased-30krad	1.0906	1.0902	-0.0004
18	35	Biased-30krad	1.0953	1.0951	-0.0002
19	35	Biased-30krad	1.0918	1.0916	-0.0002
20	35	Biased-30krad	1.088	1.0876	-0.0004
30	50	Unbiased-50krad	1.0925	1.0909	-0.0016
31	50	Unbiased-50krad	1.0917	1.0903	-0.0014
32	50	Unbiased-50krad	1.0923	1.0918	-0.0005
33	50	Unbiased-50krad	1.0943	1.0914	-0.0029
34	50	Unbiased-50krad	1.0914	1.0908	-0.0006
40	55	Biased-50krad	1.0916	1.0907	-0.0009
41	55	Biased-50krad	1.0879	1.087	-0.0009
42	55	Biased-50krad	1.0885	1.087	-0.0015
43	55	Biased-50krad	1.0877	1.0867	-0.001
44	55	Biased-50krad	1.0887	1.0894	0.0007
45	100	Unbiased-100krad	1.0906	1.089	-0.0016
46	100	Unbiased-100krad	1.0904	1.0905	0.0001
47	100	Unbiased-100krad	1.0962	1.0948	-0.0014
48	100	Unbiased-100krad	1.0911	1.0906	-0.0005
49	100	Unbiased-100krad	1.0919	1.092	0.0001
50	105	Biased-100krad	1.0882	1.0885	0.0003
51	105	Biased-100krad	1.0909	1.0893	-0.0016
52	105	Biased-100krad	1.092	1.0887	-0.0033
53	105	Biased-100krad	1.09	1.0892	-0.0008
54	105	Biased-100krad	1.0894	1.0878	-0.0016

Test Statistics ()

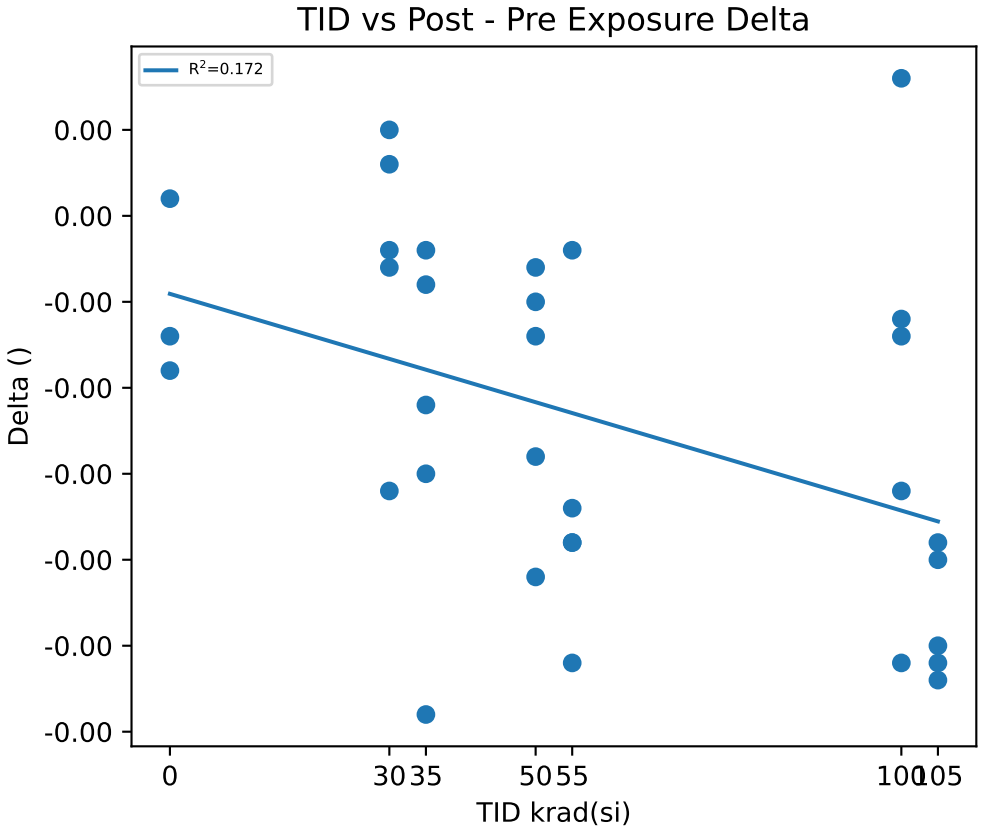
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0912	1.0915	1.092	0.00046188	1.0912	1.0914	1.0919	0.00040415	-0.0001	-3.3333e-05	0	5.7735e-05
30	1.0913	1.0924	1.0941	0.0011628	1.0911	1.0926	1.0948	0.0013989	-0.0002	0.00024	0.0007	0.00036469
35	1.088	1.0913	1.0953	0.0026452	1.0876	1.0911	1.0951	0.0027087	-0.0004	-0.0002	0.0002	0.00024495
50	1.0914	1.0924	1.0943	0.0011305	1.0903	1.091	1.0918	0.00057706	-0.0029	-0.0014	-0.0005	0.00096695
55	1.0877	1.0889	1.0916	0.0015754	1.0867	1.0882	1.0907	0.0017897	-0.0015	-0.00072	0.0007	0.00083187
100	1.0904	1.092	1.0962	0.0023965	1.089	1.0914	1.0948	0.0021868	-0.0016	-0.00066	0.0001	0.00080808
105	1.0882	1.0901	1.092	0.0014457	1.0878	1.0887	1.0893	0.00060415	-0.0033	-0.0014	0.0003	0.0013172

Device Test: 30.17 _PWRGD|FallingGood/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD

TID vs Result Stats



TID vs Post - Pre Exposure Delta



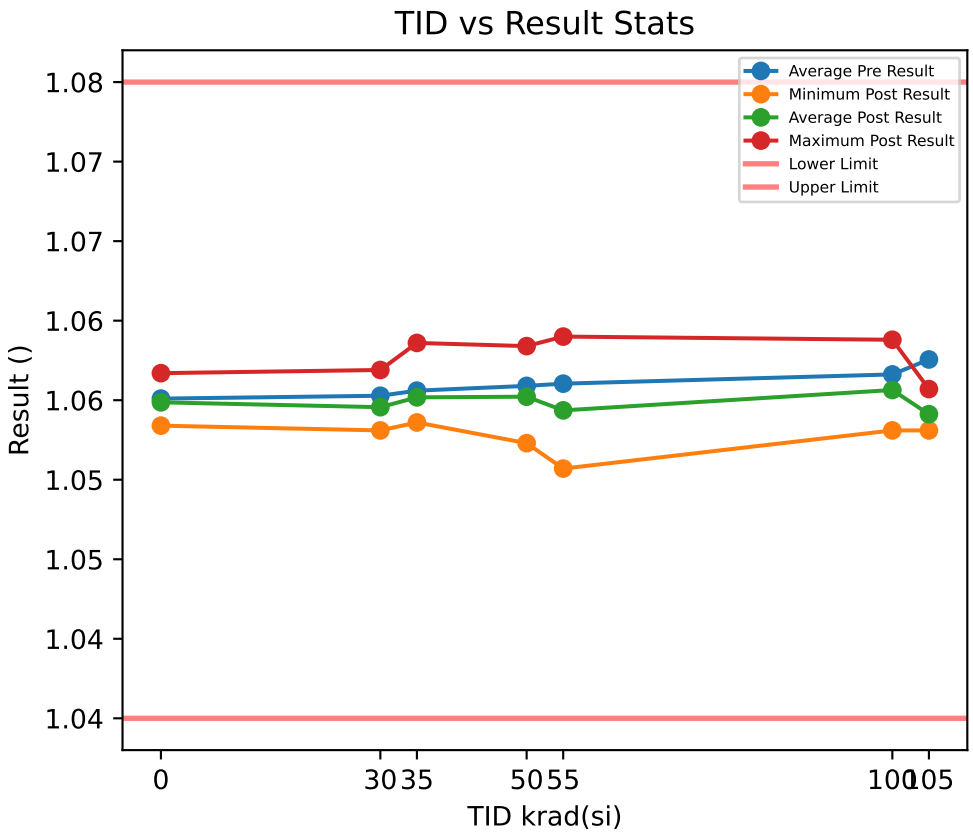
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

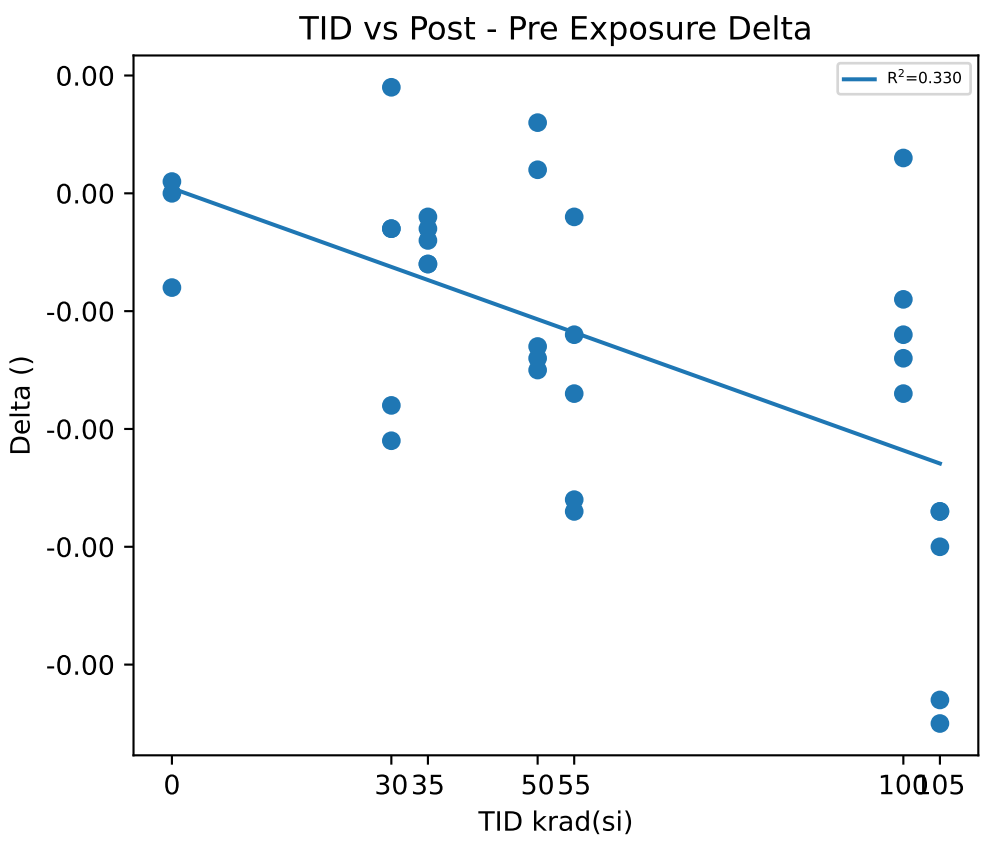
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0589	1.0582	-0.0007
2	0	CU2	1.0607	1.0608	0.0001
3	0	CU3	1.0633	1.0624	-0.0009
11	30	Unbiased-30krad	1.0598	1.0603	0.0005
12	30	Unbiased-30krad	1.0552	1.0555	0.0003
13	30	Unbiased-30krad	1.0583	1.058	-0.0003
14	30	Unbiased-30krad	1.0627	1.0625	-0.0002
15	30	Unbiased-30krad	1.0605	1.0589	-0.0016
16	35	Biased-30krad	1.0577	1.0562	-0.0015
17	35	Biased-30krad	1.0607	1.0578	-0.0029
18	35	Biased-30krad	1.0632	1.0621	-0.0011
19	35	Biased-30krad	1.0607	1.0605	-0.0002
20	35	Biased-30krad	1.0621	1.0617	-0.0004
30	50	Unbiased-50krad	1.0591	1.0584	-0.0007
31	50	Unbiased-50krad	1.0599	1.0594	-0.0005
32	50	Unbiased-50krad	1.0605	1.0584	-0.0021
33	50	Unbiased-50krad	1.061	1.0607	-0.0003
34	50	Unbiased-50krad	1.0609	1.0595	-0.0014
40	55	Biased-50krad	1.0591	1.0572	-0.0019
41	55	Biased-50krad	1.0643	1.0624	-0.0019
42	55	Biased-50krad	1.0605	1.0588	-0.0017
43	55	Biased-50krad	1.0602	1.06	-0.0002
44	55	Biased-50krad	1.0595	1.0569	-0.0026
45	100	Unbiased-100krad	1.0621	1.0595	-0.0026
46	100	Unbiased-100krad	1.0597	1.0581	-0.0016
47	100	Unbiased-100krad	1.056	1.0553	-0.0007
48	100	Unbiased-100krad	1.0633	1.0627	-0.0006
49	100	Unbiased-100krad	1.0596	1.0604	0.0008
50	105	Biased-100krad	1.0578	1.0553	-0.0025
51	105	Biased-100krad	1.0623	1.0597	-0.0026
52	105	Biased-100krad	1.0573	1.0546	-0.0027
53	105	Biased-100krad	1.0598	1.0579	-0.0019
54	105	Biased-100krad	1.0591	1.0571	-0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0589	1.061	1.0633	0.0022121	1.0582	1.0605	1.0624	0.0021197	-0.0009	-0.0005	0.0001	0.00052915
30	1.0552	1.0593	1.0627	0.0027866	1.0555	1.059	1.0625	0.0026073	-0.0016	-0.00026	0.0005	0.00082037
35	1.0577	1.0609	1.0632	0.0020645	1.0562	1.0597	1.0621	0.0025618	-0.0029	-0.00122	-0.0002	0.0010756
50	1.0591	1.0603	1.061	0.00078867	1.0584	1.0593	1.0607	0.00095237	-0.0021	-0.001	-0.0003	0.00074162
55	1.0591	1.0607	1.0643	0.0020765	1.0569	1.0591	1.0624	0.002249	-0.0026	-0.00166	-0.0002	0.00088487
100	1.056	1.0601	1.0633	0.0028041	1.0553	1.0592	1.0627	0.0027477	-0.0026	-0.00094	0.0008	0.0012641
105	1.0573	1.0593	1.0623	0.0019705	1.0546	1.0569	1.0597	0.002045	-0.0027	-0.00234	-0.0019	0.00036469

Device Test: 30.18 _PWRGD|FallingGood/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD





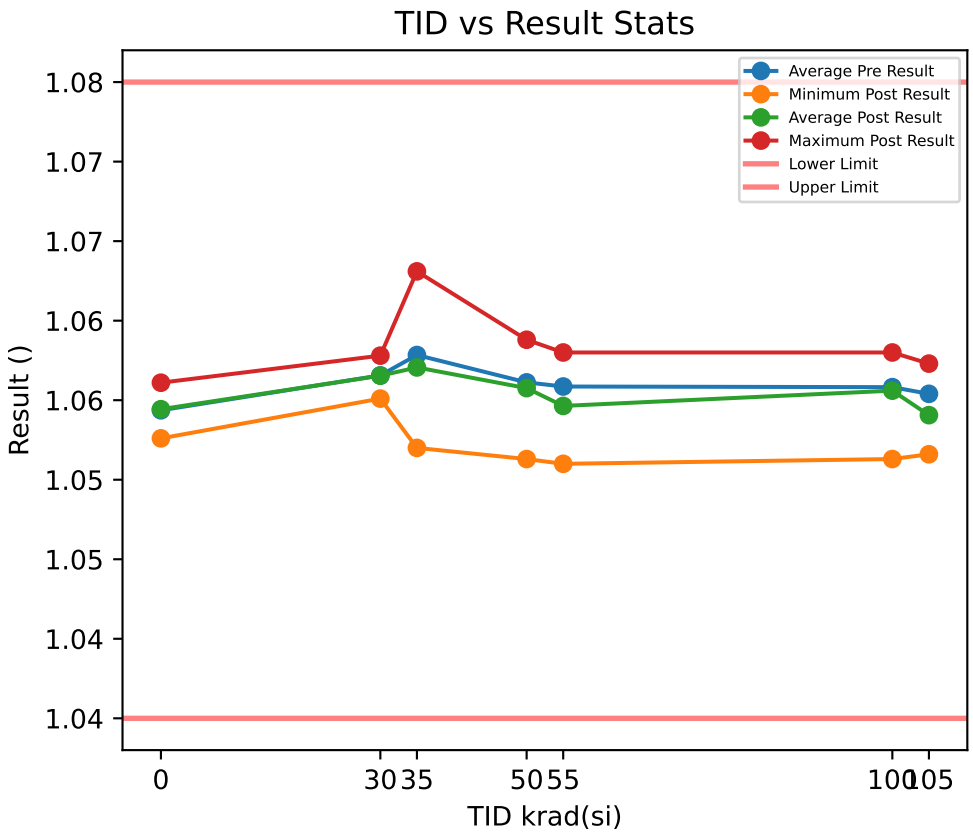
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

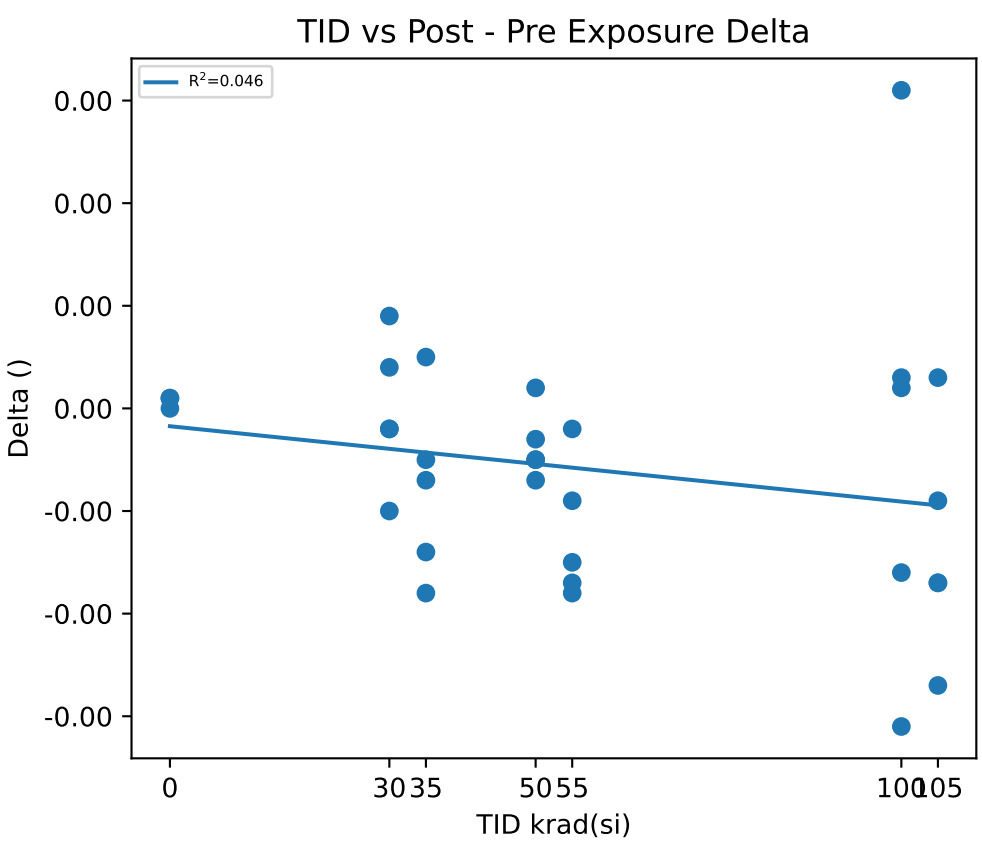
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0625	1.0617	-0.0008
2	0	CU2	1.0583	1.0584	0.0001
3	0	CU3	1.0595	1.0595	0
11	30	Unbiased-30krad	1.0598	1.0595	-0.0003
12	30	Unbiased-30krad	1.0616	1.0595	-0.0021
13	30	Unbiased-30krad	1.0606	1.0588	-0.0018
14	30	Unbiased-30krad	1.0584	1.0581	-0.0003
15	30	Unbiased-30krad	1.061	1.0619	0.0009
16	35	Biased-30krad	1.061	1.0604	-0.0006
17	35	Biased-30krad	1.0595	1.0589	-0.0006
18	35	Biased-30krad	1.0588	1.0586	-0.0002
19	35	Biased-30krad	1.0597	1.0594	-0.0003
20	35	Biased-30krad	1.064	1.0636	-0.0004
30	50	Unbiased-50krad	1.0611	1.0596	-0.0015
31	50	Unbiased-50krad	1.0587	1.0573	-0.0014
32	50	Unbiased-50krad	1.0613	1.06	-0.0013
33	50	Unbiased-50krad	1.0628	1.0634	0.0006
34	50	Unbiased-50krad	1.0606	1.0608	0.0002
40	55	Biased-50krad	1.0627	1.06	-0.0027
41	55	Biased-50krad	1.0569	1.0557	-0.0012
42	55	Biased-50krad	1.0606	1.0589	-0.0017
43	55	Biased-50krad	1.0642	1.064	-0.0002
44	55	Biased-50krad	1.0608	1.0582	-0.0026
45	100	Unbiased-100krad	1.0642	1.0625	-0.0017
46	100	Unbiased-100krad	1.0635	1.0638	0.0003
47	100	Unbiased-100krad	1.0616	1.0604	-0.0012
48	100	Unbiased-100krad	1.0598	1.0584	-0.0014
49	100	Unbiased-100krad	1.059	1.0581	-0.0009
50	105	Biased-100krad	1.0637	1.0607	-0.003
51	105	Biased-100krad	1.0624	1.0581	-0.0043
52	105	Biased-100krad	1.0616	1.0589	-0.0027
53	105	Biased-100krad	1.0632	1.0587	-0.0045
54	105	Biased-100krad	1.0619	1.0592	-0.0027

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0583	1.0601	1.0625	0.0021633	1.0584	1.0599	1.0617	0.0016803	-0.0008	-0.00023333	0.0001	0.00049329
30	1.0584	1.0603	1.0616	0.0012377	1.0581	1.0596	1.0619	0.0014311	-0.0021	-0.00072	0.0009	0.0012296
35	1.0588	1.0606	1.064	0.0020603	1.0586	1.0602	1.0636	0.0020303	-0.0006	-0.00042	-0.0002	0.00017889
50	1.0587	1.0609	1.0628	0.0014782	1.0573	1.0602	1.0634	0.0022027	-0.0015	-0.00068	0.0006	0.0009985
55	1.0569	1.061	1.0642	0.0027446	1.0557	1.0594	1.064	0.0030369	-0.0027	-0.00168	-0.0002	0.0010378
100	1.059	1.0616	1.0642	0.0022565	1.0581	1.0606	1.0638	0.0024986	-0.0017	-0.00098	0.0003	0.00077266
105	1.0616	1.0626	1.0637	0.0008792	1.0581	1.0591	1.0607	0.00097057	-0.0045	-0.00344	-0.0027	0.00088769

Device Test: 30.19 _PWRGD|FallingGood/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD





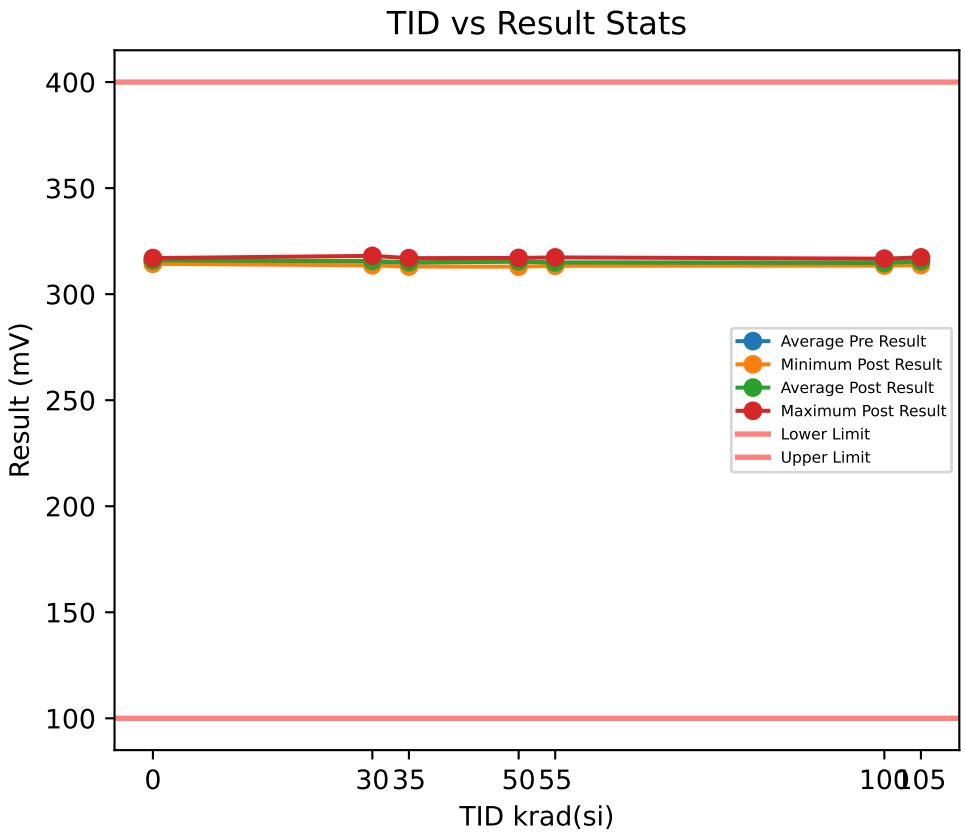
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

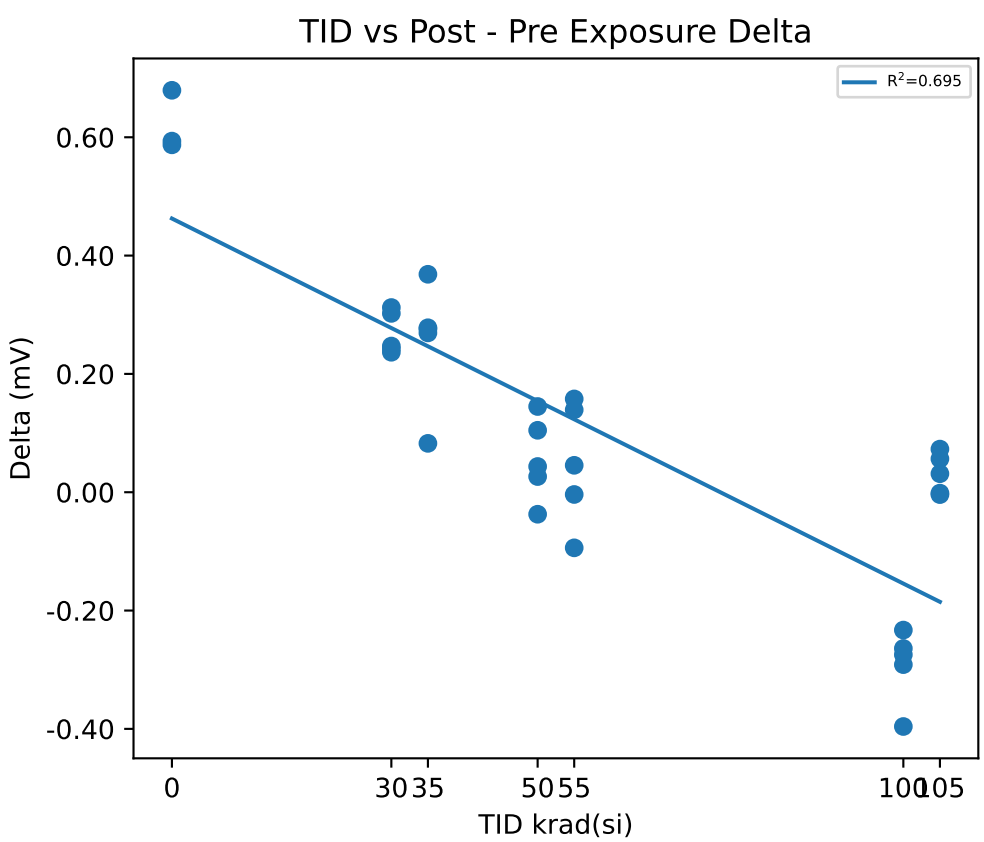
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.061	1.0611	0.0001
2	0	CU2	1.0595	1.0596	0.0001
3	0	CU3	1.0576	1.0576	0
11	30	Unbiased-30krad	1.0629	1.0627	-0.0002
12	30	Unbiased-30krad	1.0624	1.0628	0.0004
13	30	Unbiased-30krad	1.062	1.0618	-0.0002
14	30	Unbiased-30krad	1.0611	1.0601	-0.001
15	30	Unbiased-30krad	1.0594	1.0603	0.0009
16	35	Biased-30krad	1.061	1.0603	-0.0007
17	35	Biased-30krad	1.0662	1.0648	-0.0014
18	35	Biased-30krad	1.0565	1.057	0.0005
19	35	Biased-30krad	1.0699	1.0681	-0.0018
20	35	Biased-30krad	1.0606	1.0601	-0.0005
30	50	Unbiased-50krad	1.0636	1.0638	0.0002
31	50	Unbiased-50krad	1.0621	1.0616	-0.0005
32	50	Unbiased-50krad	1.0622	1.0617	-0.0005
33	50	Unbiased-50krad	1.0607	1.0604	-0.0003
34	50	Unbiased-50krad	1.057	1.0563	-0.0007
40	55	Biased-50krad	1.0639	1.063	-0.0009
41	55	Biased-50krad	1.0599	1.0597	-0.0002
42	55	Biased-50krad	1.0575	1.056	-0.0015
43	55	Biased-50krad	1.0608	1.059	-0.0018
44	55	Biased-50krad	1.0622	1.0605	-0.0017
45	100	Unbiased-100krad	1.0568	1.0599	0.0031
46	100	Unbiased-100krad	1.0628	1.063	0.0002
47	100	Unbiased-100krad	1.0594	1.0563	-0.0031
48	100	Unbiased-100krad	1.0616	1.0619	0.0003
49	100	Unbiased-100krad	1.0635	1.0619	-0.0016
50	105	Biased-100krad	1.0565	1.0568	0.0003
51	105	Biased-100krad	1.0617	1.06	-0.0017
52	105	Biased-100krad	1.064	1.0623	-0.0017
53	105	Biased-100krad	1.0593	1.0566	-0.0027
54	105	Biased-100krad	1.0605	1.0596	-0.0009

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0576	1.0594	1.061	0.0017039	1.0576	1.0594	1.0611	0.0017559	0	6.6667e-05	0.0001	5.7735e-05
30	1.0594	1.0616	1.0629	0.0013759	1.0601	1.0615	1.0628	0.0012857	-0.001	-2e-05	0.0009	0.00071554
35	1.0565	1.0628	1.0699	0.0052377	1.057	1.0621	1.0681	0.0043741	-0.0018	-0.00078	0.0005	0.00088713
50	1.057	1.0611	1.0636	0.0025213	1.0563	1.0608	1.0638	0.0027772	-0.0007	-0.00036	0.0002	0.00034351
55	1.0575	1.0609	1.0639	0.002411	1.056	1.0596	1.063	0.0025344	-0.0018	-0.00122	-0.0002	0.00066858
100	1.0568	1.0608	1.0635	0.0027335	1.0563	1.0606	1.063	0.0026514	-0.0031	-0.00022	0.0031	0.0023274
105	1.0565	1.0604	1.064	0.0027875	1.0566	1.0591	1.0623	0.0023891	-0.0027	-0.00134	0.0003	0.0011171

Device Test: 30.2 _PWRGD|VOL/PWRGD2/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW





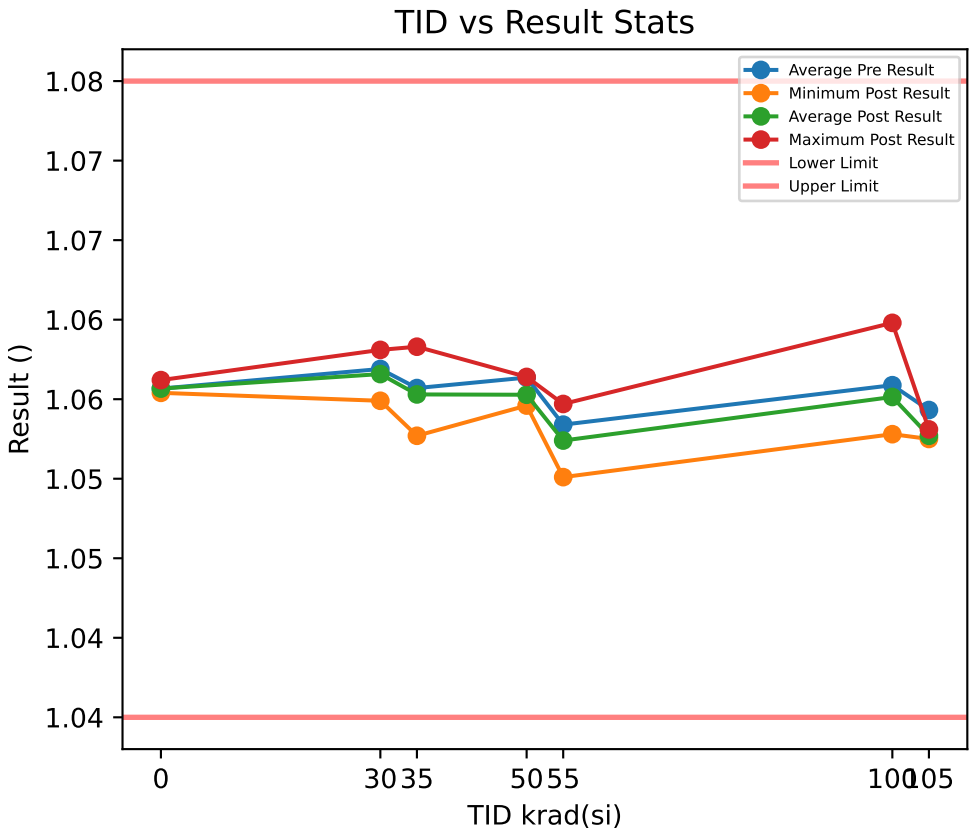
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

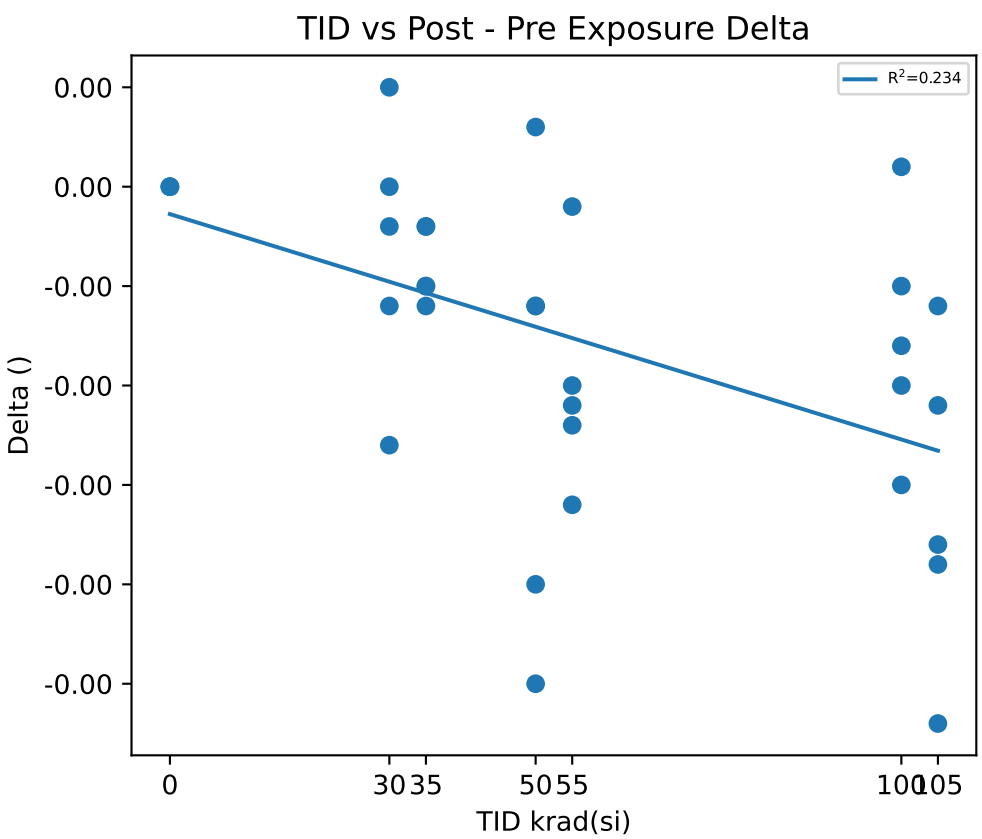
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	315.79	316.46	0.6794
2	0	CU2	313.72	314.31	0.5935
3	0	CU3	316.43	317.02	0.5872
11	30	Unbiased-30krad	313.39	313.69	0.3023
12	30	Unbiased-30krad	316.56	316.81	0.2471
13	30	Unbiased-30krad	313.35	313.59	0.2366
14	30	Unbiased-30krad	315.84	316.09	0.2423
15	30	Unbiased-30krad	317.75	318.06	0.3122
16	35	Biased-30krad	316.34	316.71	0.3684
17	35	Biased-30krad	315.05	315.32	0.278
18	35	Biased-30krad	316.71	316.98	0.2693
19	35	Biased-30krad	312.81	313.08	0.276
20	35	Biased-30krad	312.92	313.01	0.0826
30	50	Unbiased-50krad	315.74	315.85	0.1047
31	50	Unbiased-50krad	312.84	312.98	0.1449
32	50	Unbiased-50krad	316.3	316.35	0.0435
33	50	Unbiased-50krad	315.11	315.07	-0.0372
34	50	Unbiased-50krad	317.06	317.09	0.0265
40	55	Biased-50krad	313.38	313.38	-0.0038
41	55	Biased-50krad	314.34	314.5	0.1577
42	55	Biased-50krad	317.19	317.33	0.1393
43	55	Biased-50krad	315.82	315.87	0.0455
44	55	Biased-50krad	313.52	313.43	-0.094
45	100	Unbiased-100krad	313.74	313.46	-0.2746
46	100	Unbiased-100krad	315.57	315.34	-0.233
47	100	Unbiased-100krad	313.93	313.53	-0.396
48	100	Unbiased-100krad	314.6	314.31	-0.2914
49	100	Unbiased-100krad	317	316.74	-0.2641
50	105	Biased-100krad	316.5	316.56	0.0565
51	105	Biased-100krad	313.66	313.69	0.0313
52	105	Biased-100krad	315.5	315.57	0.0729
53	105	Biased-100krad	314.35	314.34	-0.0015
54	105	Biased-100krad	317.35	317.35	-0.004

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	313.72	315.31	316.43	1.4162	314.31	315.93	317.02	1.4289	0.5872	0.62003	0.6794	0.051509
30	313.35	315.38	317.75	1.9544	313.59	315.65	318.06	1.9628	0.2366	0.2681	0.3122	0.036102
35	312.81	314.77	316.71	1.8417	313.01	315.02	316.98	1.9098	0.0826	0.25486	0.3684	0.10459
50	312.84	315.41	317.06	1.6075	312.98	315.47	317.09	1.5706	-0.0372	0.05648	0.1449	0.070687
55	313.38	314.85	317.19	1.6282	313.38	314.9	317.33	1.6946	-0.094	0.04894	0.1577	0.10395
100	313.74	314.97	317	1.345	313.46	314.68	316.74	1.3793	-0.396	-0.29182	-0.233	0.062005
105	313.66	315.47	317.35	1.511	313.69	315.5	317.35	1.5111	-0.004	0.03104	0.0729	0.034232

Device Test: 30.20 _PWRGD|FallingGood/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD





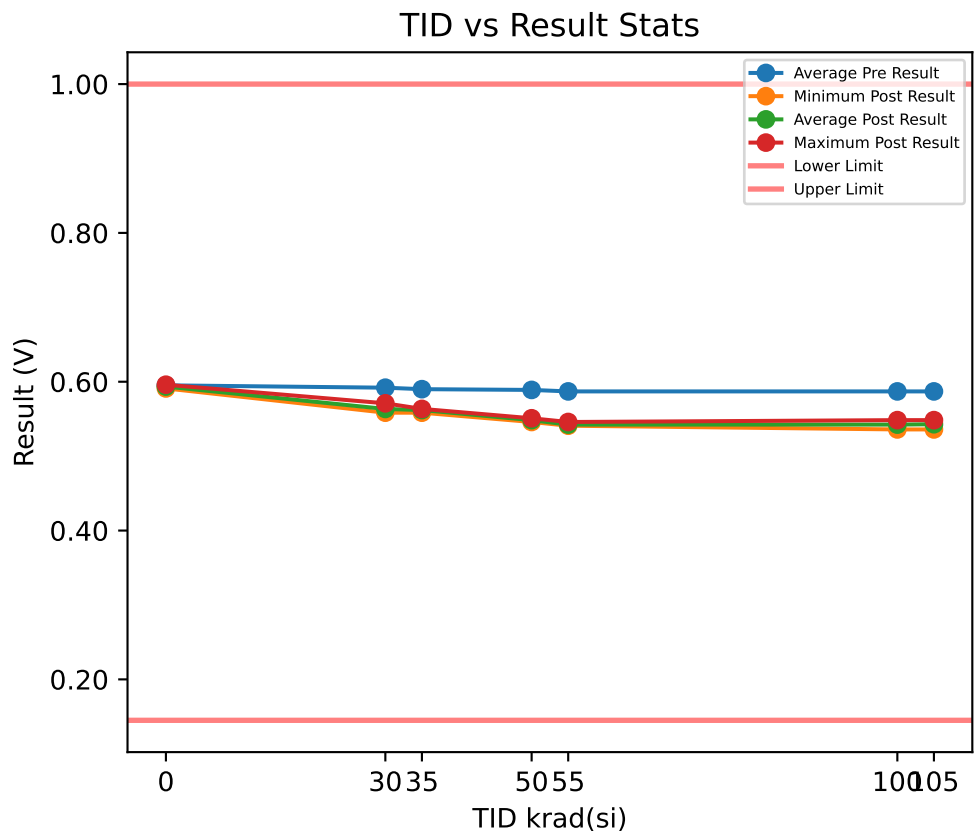
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

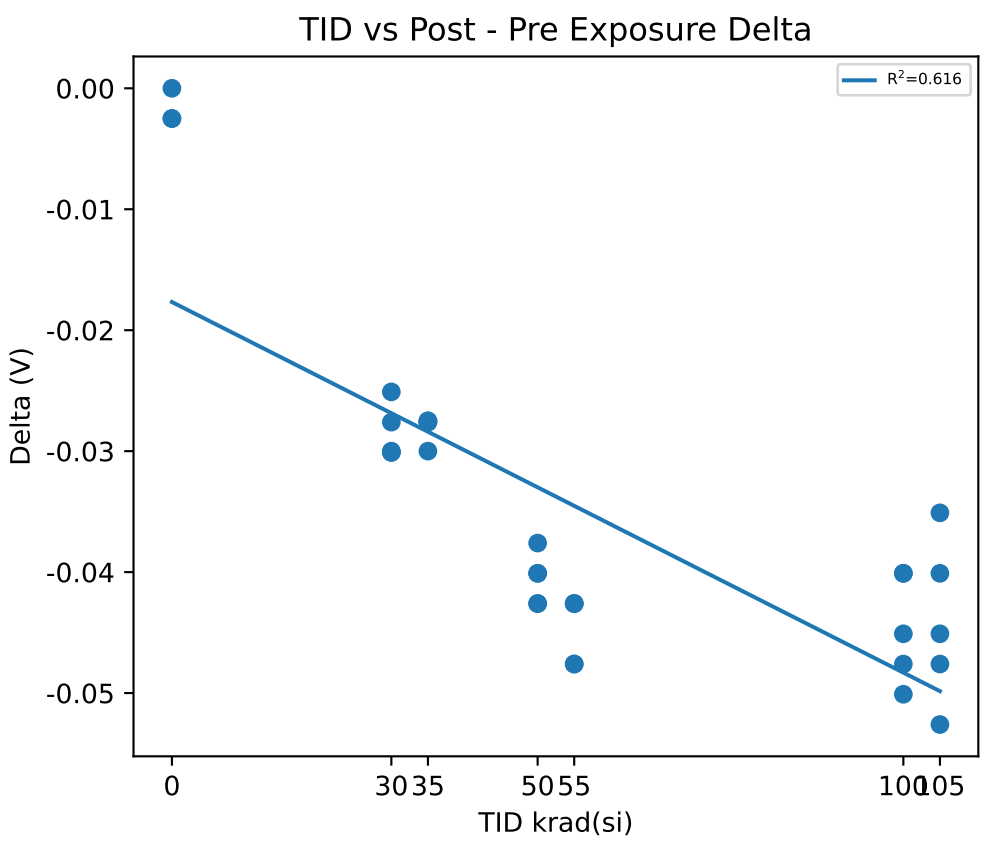
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0604	1.0604	0
2	0	CU2	1.0612	1.0612	0
3	0	CU3	1.0604	1.0604	0
11	30	Unbiased-30krad	1.0612	1.0599	-0.0013
12	30	Unbiased-30krad	1.0627	1.0621	-0.0006
13	30	Unbiased-30krad	1.0606	1.0611	0.0005
14	30	Unbiased-30krad	1.0633	1.0631	-0.0002
15	30	Unbiased-30krad	1.0617	1.0617	0
16	35	Biased-30krad	1.0608	1.0602	-0.0006
17	35	Biased-30krad	1.0599	1.0594	-0.0005
18	35	Biased-30krad	1.0635	1.0633	-0.0002
19	35	Biased-30krad	1.0611	1.0609	-0.0002
20	35	Biased-30krad	1.0582	1.0577	-0.0005
30	50	Unbiased-50krad	1.0626	1.0601	-0.0025
31	50	Unbiased-50krad	1.0602	1.0596	-0.0006
32	50	Unbiased-50krad	1.0599	1.0602	0.0003
33	50	Unbiased-50krad	1.0634	1.0614	-0.002
34	50	Unbiased-50krad	1.0607	1.0601	-0.0006
40	55	Biased-50krad	1.0608	1.0597	-0.0011
41	55	Biased-50krad	1.058	1.057	-0.001
42	55	Biased-50krad	1.0567	1.0551	-0.0016
43	55	Biased-50krad	1.0577	1.0565	-0.0012
44	55	Biased-50krad	1.0588	1.0587	-0.0001
45	100	Unbiased-100krad	1.0599	1.0589	-0.001
46	100	Unbiased-100krad	1.0596	1.0597	0.0001
47	100	Unbiased-100krad	1.0653	1.0648	-0.0005
48	100	Unbiased-100krad	1.0593	1.0578	-0.0015
49	100	Unbiased-100krad	1.0603	1.0595	-0.0008
50	105	Biased-100krad	1.0583	1.0577	-0.0006
51	105	Biased-100krad	1.0593	1.0575	-0.0018
52	105	Biased-100krad	1.0603	1.0576	-0.0027
53	105	Biased-100krad	1.0592	1.0581	-0.0011
54	105	Biased-100krad	1.0595	1.0576	-0.0019

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0604	1.0607	1.0612	0.00046188	1.0604	1.0607	1.0612	0.00046188	0	0	0	0
30	1.0606	1.0619	1.0633	0.0010977	1.0599	1.0616	1.0631	0.0011883	-0.0013	-0.00032	0.0005	0.00067602
35	1.0582	1.0607	1.0635	0.00193	1.0577	1.0603	1.0633	0.0020579	-0.0006	-0.0004	-0.0002	0.00018708
50	1.0599	1.0614	1.0634	0.0015502	1.0596	1.0603	1.0614	0.00066858	-0.0025	-0.00108	0.0003	0.0011432
55	1.0567	1.0584	1.0608	0.0015379	1.0551	1.0574	1.0597	0.0018193	-0.0016	-0.001	-0.0001	0.00055227
100	1.0593	1.0609	1.0653	0.0024984	1.0578	1.0601	1.0648	0.002708	-0.0015	-0.00074	0.0001	0.00059414
105	1.0583	1.0593	1.0603	0.00071554	1.0575	1.0577	1.0581	0.00023452	-0.0027	-0.00162	-0.0006	0.00080436

Device Test: 30.25 _MinVin|Valid/PWRGD1/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_OUTPUT





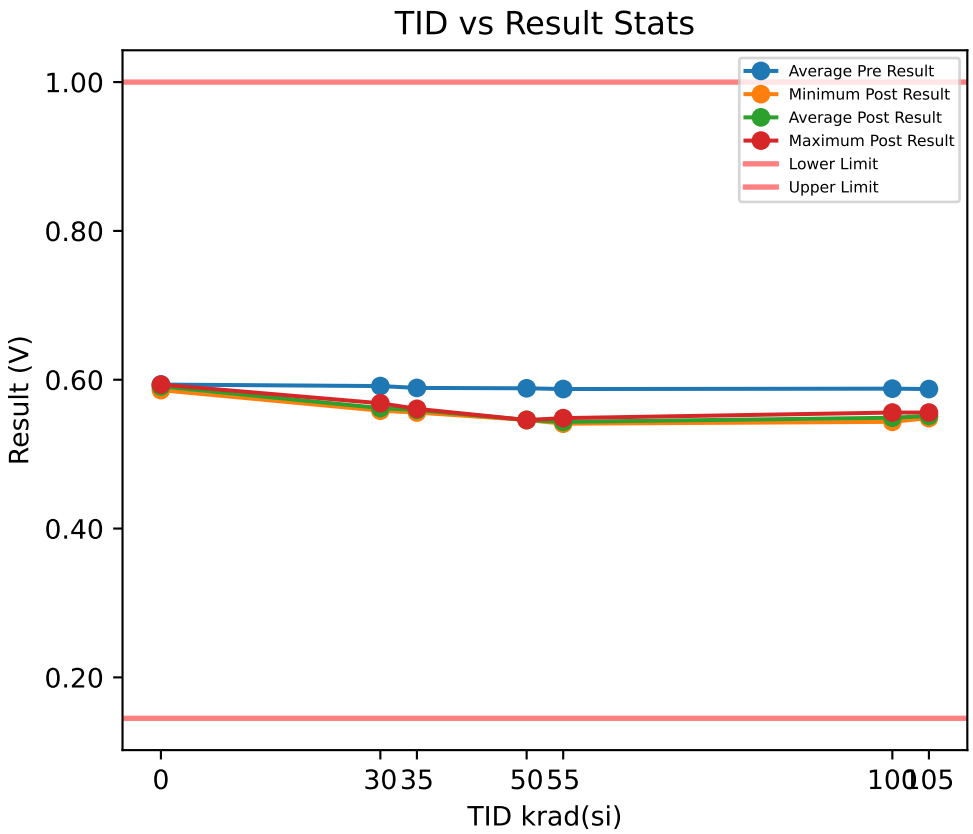
Test Results (Lower Limit = 0.145, Upper Limit = 1.0 (V))

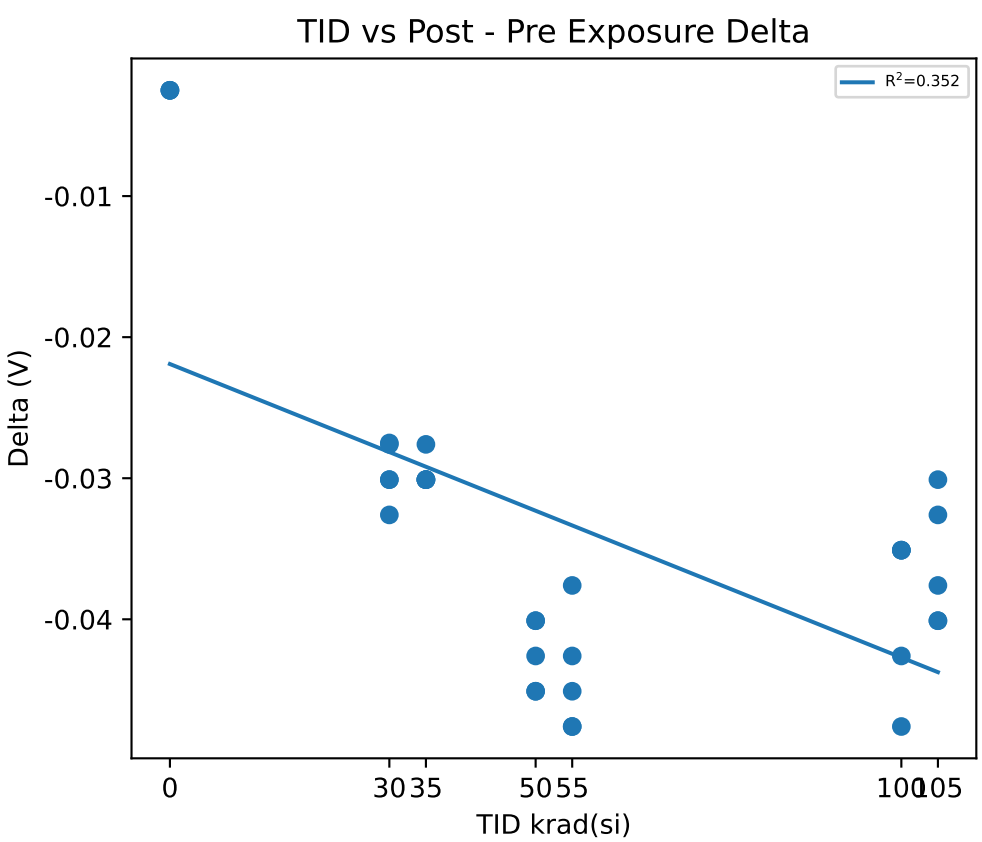
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.596	0.5935	-0.0025
2	0	CU2	0.591	0.591	0
3	0	CU3	0.5985	0.596	-0.0025
11	30	Unbiased-30krad	0.5885	0.5609	-0.0276
12	30	Unbiased-30krad	0.591	0.5659	-0.0251
13	30	Unbiased-30krad	0.5885	0.5584	-0.0301
14	30	Unbiased-30krad	0.591	0.5609	-0.0301
15	30	Unbiased-30krad	0.601	0.571	-0.03
16	35	Biased-30krad	0.591	0.5635	-0.0275
17	35	Biased-30krad	0.591	0.5635	-0.0275
18	35	Biased-30krad	0.5935	0.5635	-0.03
19	35	Biased-30krad	0.586	0.5584	-0.0276
20	35	Biased-30krad	0.5885	0.5609	-0.0276
30	50	Unbiased-50krad	0.586	0.5484	-0.0376
31	50	Unbiased-50krad	0.586	0.5459	-0.0401
32	50	Unbiased-50krad	0.5935	0.5509	-0.0426
33	50	Unbiased-50krad	0.586	0.5459	-0.0401
34	50	Unbiased-50krad	0.5935	0.5509	-0.0426
40	55	Biased-50krad	0.5835	0.5409	-0.0426
41	55	Biased-50krad	0.5885	0.5459	-0.0426
42	55	Biased-50krad	0.591	0.5434	-0.0476
43	55	Biased-50krad	0.5885	0.5409	-0.0476
44	55	Biased-50krad	0.5835	0.5409	-0.0426
45	100	Unbiased-100krad	0.586	0.5359	-0.0501
46	100	Unbiased-100krad	0.586	0.5384	-0.0476
47	100	Unbiased-100krad	0.586	0.5459	-0.0401
48	100	Unbiased-100krad	0.5885	0.5484	-0.0401
49	100	Unbiased-100krad	0.5885	0.5434	-0.0451
50	105	Biased-100krad	0.5885	0.5359	-0.0526
51	105	Biased-100krad	0.586	0.5459	-0.0401
52	105	Biased-100krad	0.5885	0.5434	-0.0451
53	105	Biased-100krad	0.5835	0.5484	-0.0351
54	105	Biased-100krad	0.5885	0.5409	-0.0476

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.591	0.59517	0.5985	0.0038188	0.591	0.5935	0.596	0.0025	-0.0025	-0.0016667	0	0.0014434
30	0.5885	0.592	0.601	0.0051841	0.5584	0.56342	0.571	0.0050376	-0.0301	-0.02858	-0.0251	0.0022197
35	0.586	0.59	0.5935	0.0028504	0.5584	0.56196	0.5635	0.0022865	-0.03	-0.02804	-0.0275	0.0010968
50	0.586	0.589	0.5935	0.0041079	0.5459	0.5484	0.5509	0.0025	-0.0426	-0.0406	-0.0376	0.0020917
55	0.5835	0.587	0.591	0.0033541	0.5409	0.5424	0.5459	0.0022361	-0.0476	-0.0446	-0.0426	0.0027386
100	0.586	0.587	0.5885	0.0013693	0.5359	0.5424	0.5484	0.0051841	-0.0501	-0.0446	-0.0401	0.0044721
105	0.5835	0.587	0.5885	0.0022361	0.5359	0.5429	0.5484	0.0048088	-0.0526	-0.0441	-0.0351	0.0067546

Device Test: 30.26 _MinVin|Valid/PWRGD2/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_OUTPUT





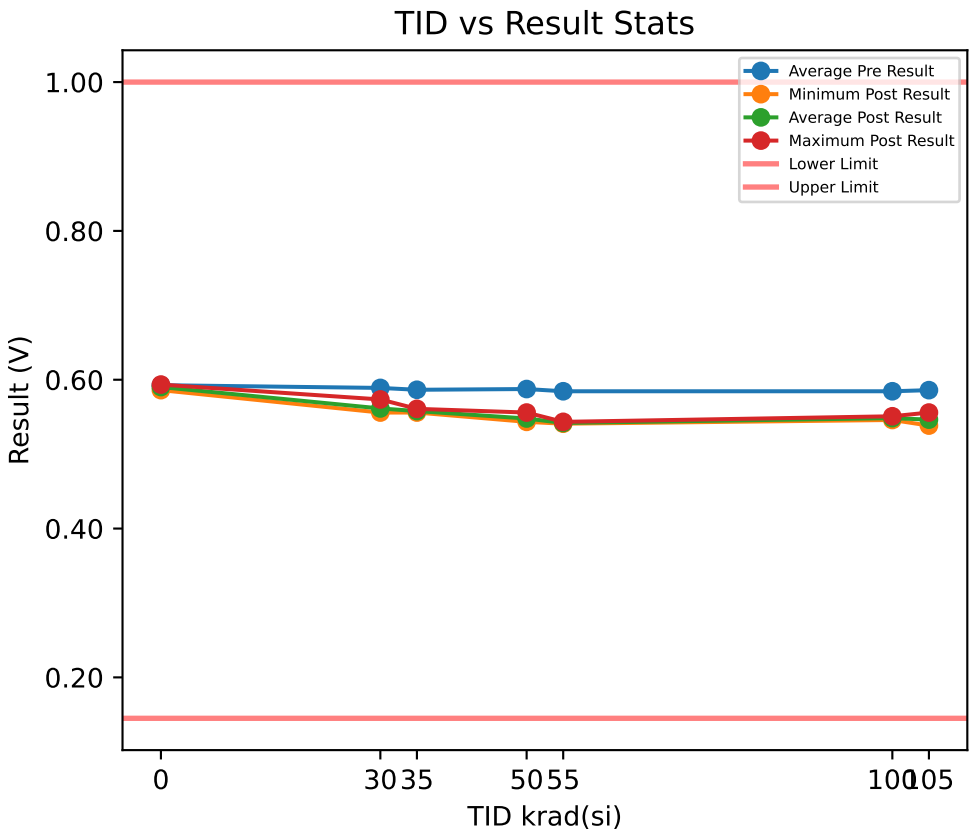
Test Results (Lower Limit = 0.145, Upper Limit = 1.0 (V))

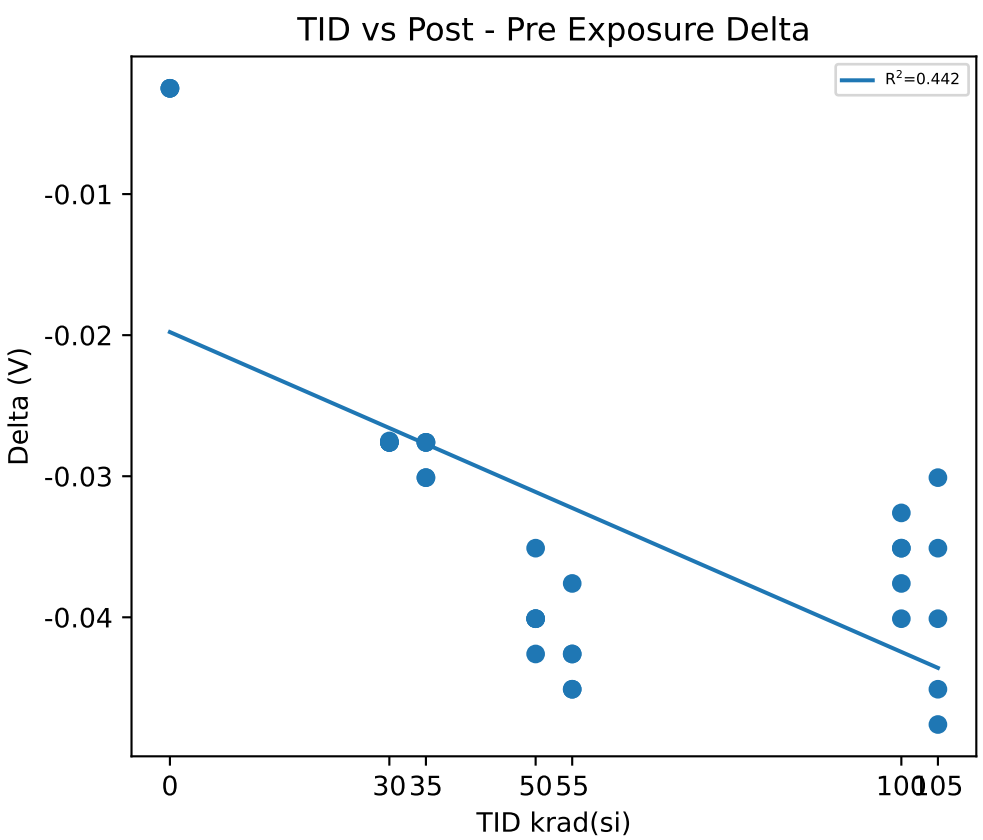
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.596	0.5935	-0.0025
2	0	CU2	0.5885	0.586	-0.0025
3	0	CU3	0.596	0.5935	-0.0025
11	30	Unbiased-30krad	0.5885	0.5609	-0.0276
12	30	Unbiased-30krad	0.591	0.5635	-0.0275
13	30	Unbiased-30krad	0.5885	0.5584	-0.0301
14	30	Unbiased-30krad	0.591	0.5584	-0.0326
15	30	Unbiased-30krad	0.5985	0.5684	-0.0301
16	35	Biased-30krad	0.591	0.5609	-0.0301
17	35	Biased-30krad	0.591	0.5609	-0.0301
18	35	Biased-30krad	0.5885	0.5609	-0.0276
19	35	Biased-30krad	0.586	0.5559	-0.0301
20	35	Biased-30krad	0.5885	0.5584	-0.0301
30	50	Unbiased-50krad	0.586	0.5459	-0.0401
31	50	Unbiased-50krad	0.586	0.5459	-0.0401
32	50	Unbiased-50krad	0.591	0.5459	-0.0451
33	50	Unbiased-50krad	0.5885	0.5459	-0.0426
34	50	Unbiased-50krad	0.591	0.5459	-0.0451
40	55	Biased-50krad	0.586	0.5484	-0.0376
41	55	Biased-50krad	0.5885	0.5434	-0.0451
42	55	Biased-50krad	0.591	0.5434	-0.0476
43	55	Biased-50krad	0.5885	0.5409	-0.0476
44	55	Biased-50krad	0.5835	0.5409	-0.0426
45	100	Unbiased-100krad	0.586	0.5509	-0.0351
46	100	Unbiased-100krad	0.586	0.5434	-0.0426
47	100	Unbiased-100krad	0.586	0.5509	-0.0351
48	100	Unbiased-100krad	0.591	0.5559	-0.0351
49	100	Unbiased-100krad	0.591	0.5434	-0.0476
50	105	Biased-100krad	0.5885	0.5509	-0.0376
51	105	Biased-100krad	0.586	0.5559	-0.0301
52	105	Biased-100krad	0.5885	0.5484	-0.0401
53	105	Biased-100krad	0.5835	0.5509	-0.0326
54	105	Biased-100krad	0.591	0.5509	-0.0401

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5885	0.5935	0.596	0.0043301	0.586	0.591	0.5935	0.0043301	-0.0025	-0.0025	-0.0025	6.4067e-17
30	0.5885	0.5915	0.5985	0.0041079	0.5584	0.56192	0.5684	0.0041925	-0.0326	-0.02958	-0.0275	0.0021159
35	0.586	0.589	0.591	0.0020917	0.5559	0.5594	0.5609	0.0022361	-0.0301	-0.0296	-0.0276	0.001118
50	0.586	0.5885	0.591	0.0025	0.5459	0.5459	0.5459	0	-0.0451	-0.0426	-0.0401	0.0025
55	0.5835	0.5875	0.591	0.0028504	0.5409	0.5434	0.5484	0.0030619	-0.0476	-0.0441	-0.0376	0.0041833
100	0.586	0.588	0.591	0.0027386	0.5434	0.5489	0.5559	0.0054199	-0.0476	-0.0391	-0.0351	0.0057554
105	0.5835	0.5875	0.591	0.0028504	0.5484	0.5514	0.5559	0.0027386	-0.0401	-0.0361	-0.0301	0.0045415

Device Test: 30.27 _MinVin|Valid/PWRGD3/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_OUTPUT





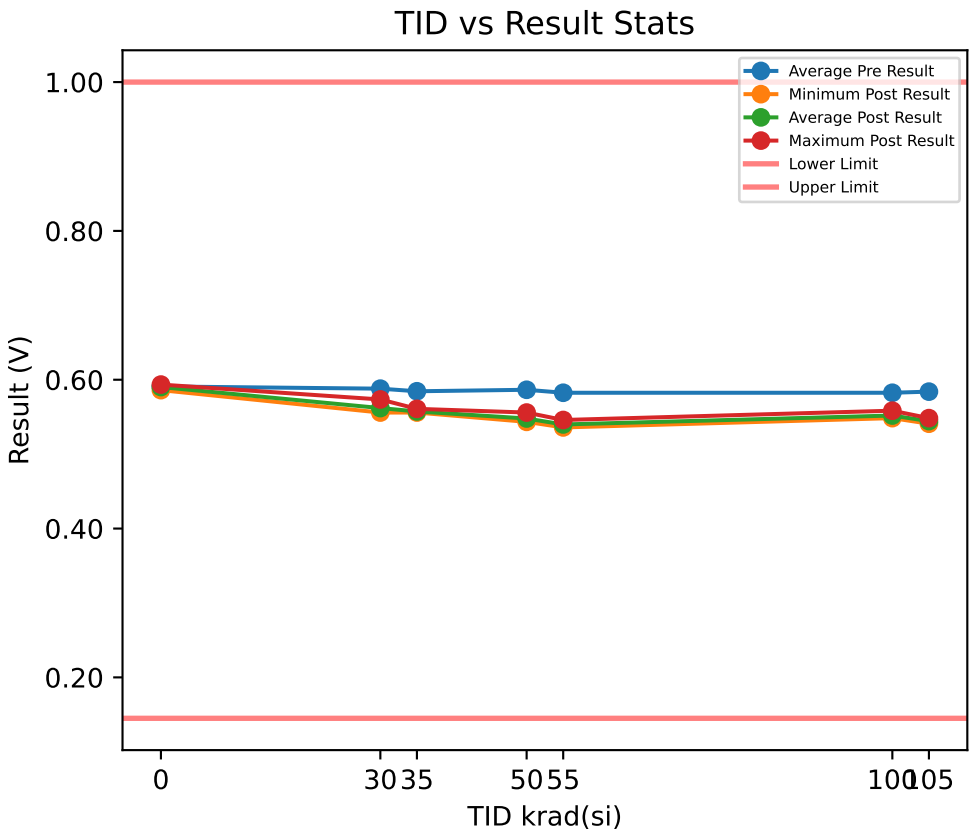
Test Results (Lower Limit = 0.145, Upper Limit = 1.0 (V))

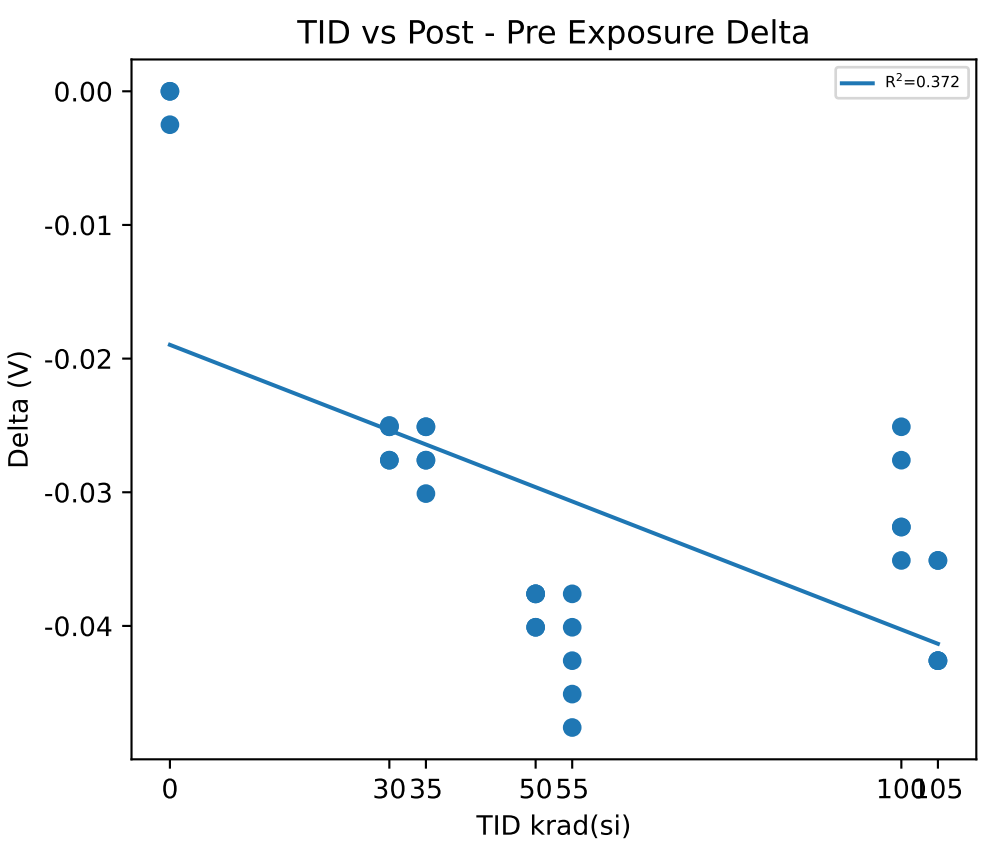
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.5935	0.591	-0.0025
2	0	CU2	0.5885	0.586	-0.0025
3	0	CU3	0.596	0.5935	-0.0025
11	30	Unbiased-30krad	0.5885	0.5609	-0.0276
12	30	Unbiased-30krad	0.586	0.5584	-0.0276
13	30	Unbiased-30krad	0.5835	0.5559	-0.0276
14	30	Unbiased-30krad	0.586	0.5584	-0.0276
15	30	Unbiased-30krad	0.601	0.5735	-0.0275
16	35	Biased-30krad	0.5885	0.5609	-0.0276
17	35	Biased-30krad	0.586	0.5584	-0.0276
18	35	Biased-30krad	0.586	0.5559	-0.0301
19	35	Biased-30krad	0.586	0.5559	-0.0301
20	35	Biased-30krad	0.586	0.5584	-0.0276
30	50	Unbiased-50krad	0.5835	0.5484	-0.0351
31	50	Unbiased-50krad	0.5835	0.5434	-0.0401
32	50	Unbiased-50krad	0.5885	0.5459	-0.0426
33	50	Unbiased-50krad	0.586	0.5459	-0.0401
34	50	Unbiased-50krad	0.596	0.5559	-0.0401
40	55	Biased-50krad	0.5835	0.5409	-0.0426
41	55	Biased-50krad	0.586	0.5409	-0.0451
42	55	Biased-50krad	0.5885	0.5434	-0.0451
43	55	Biased-50krad	0.5835	0.5409	-0.0426
44	55	Biased-50krad	0.581	0.5434	-0.0376
45	100	Unbiased-100krad	0.581	0.5459	-0.0351
46	100	Unbiased-100krad	0.5835	0.5509	-0.0326
47	100	Unbiased-100krad	0.5835	0.5484	-0.0351
48	100	Unbiased-100krad	0.586	0.5484	-0.0376
49	100	Unbiased-100krad	0.5885	0.5484	-0.0401
50	105	Biased-100krad	0.5885	0.5434	-0.0451
51	105	Biased-100krad	0.5835	0.5484	-0.0351
52	105	Biased-100krad	0.586	0.5459	-0.0401
53	105	Biased-100krad	0.586	0.5559	-0.0301
54	105	Biased-100krad	0.586	0.5384	-0.0476

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5885	0.59267	0.596	0.0038188	0.586	0.59017	0.5935	0.0038188	-0.0025	-0.0025	-0.0025	6.4161e-17
30	0.5835	0.589	0.601	0.0069372	0.5559	0.56142	0.5735	0.0069805	-0.0276	-0.02758	-0.0275	4.4721e-05
35	0.586	0.5865	0.5885	0.001118	0.5559	0.5579	0.5609	0.0020917	-0.0301	-0.0286	-0.0276	0.0013693
50	0.5835	0.5875	0.596	0.0051841	0.5434	0.5479	0.5559	0.0048088	-0.0426	-0.0396	-0.0351	0.0027386
55	0.581	0.5845	0.5885	0.0028504	0.5409	0.5419	0.5434	0.0013693	-0.0451	-0.0426	-0.0376	0.0030619
100	0.581	0.5845	0.5885	0.0028504	0.5459	0.5484	0.5509	0.0017678	-0.0401	-0.0361	-0.0326	0.0028504
105	0.5835	0.586	0.5885	0.0017678	0.5384	0.5464	0.5559	0.0064711	-0.0476	-0.0396	-0.0301	0.0071589

Device Test: 30.28 _MinVin|Valid/PWRGD4/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_OUTPUT





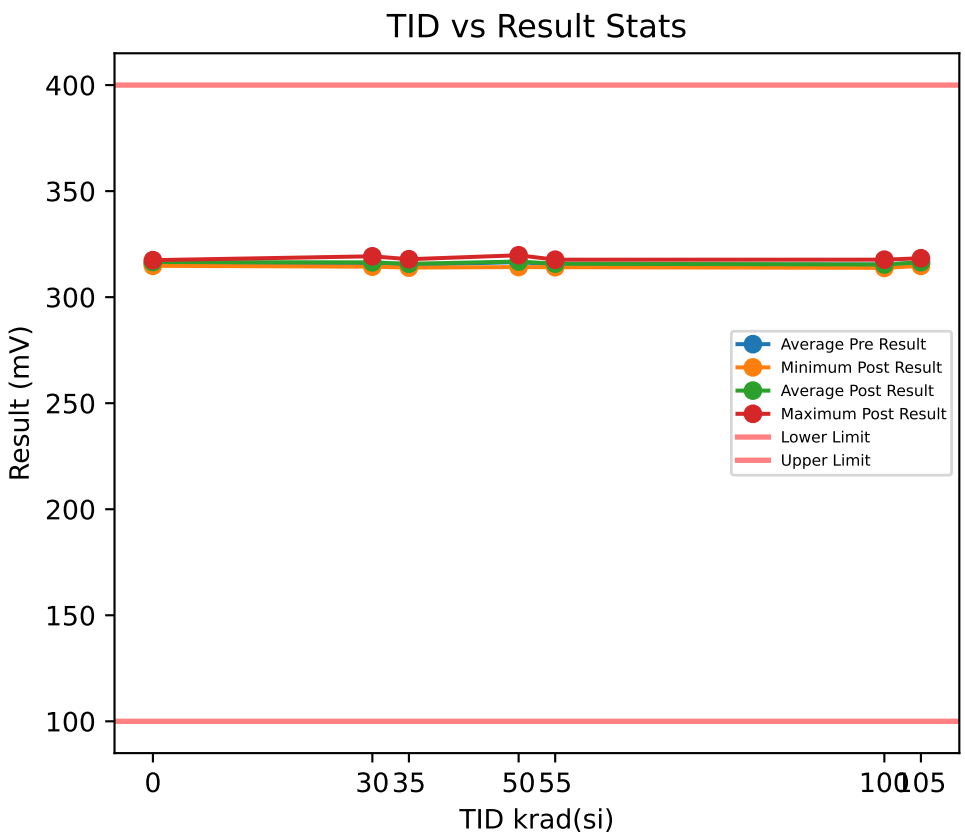
Test Results (Lower Limit = 0.145, Upper Limit = 1.0 (V))

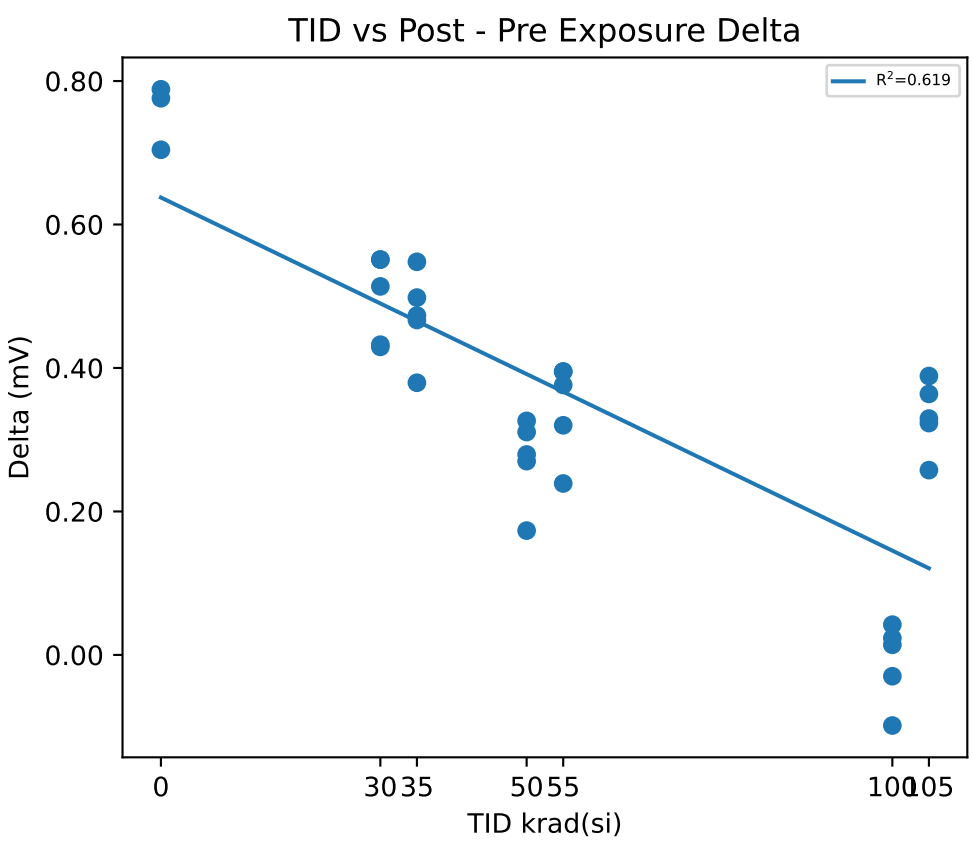
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.5935	0.591	-0.0025
2	0	CU2	0.586	0.586	0
3	0	CU3	0.5935	0.5935	0
11	30	Unbiased-30krad	0.586	0.5609	-0.0251
12	30	Unbiased-30krad	0.586	0.5609	-0.0251
13	30	Unbiased-30krad	0.5835	0.5559	-0.0276
14	30	Unbiased-30krad	0.586	0.5584	-0.0276
15	30	Unbiased-30krad	0.5985	0.5735	-0.025
16	35	Biased-30krad	0.586	0.5609	-0.0251
17	35	Biased-30krad	0.5835	0.5584	-0.0251
18	35	Biased-30krad	0.586	0.5559	-0.0301
19	35	Biased-30krad	0.5835	0.5559	-0.0276
20	35	Biased-30krad	0.5835	0.5559	-0.0276
30	50	Unbiased-50krad	0.5835	0.5459	-0.0376
31	50	Unbiased-50krad	0.5835	0.5459	-0.0376
32	50	Unbiased-50krad	0.586	0.5484	-0.0376
33	50	Unbiased-50krad	0.5835	0.5434	-0.0401
34	50	Unbiased-50krad	0.596	0.5559	-0.0401
40	55	Biased-50krad	0.581	0.5409	-0.0401
41	55	Biased-50krad	0.5835	0.5459	-0.0376
42	55	Biased-50krad	0.586	0.5384	-0.0476
43	55	Biased-50krad	0.5835	0.5384	-0.0451
44	55	Biased-50krad	0.5785	0.5359	-0.0426
45	100	Unbiased-100krad	0.581	0.5484	-0.0326
46	100	Unbiased-100krad	0.581	0.5534	-0.0276
47	100	Unbiased-100krad	0.581	0.5484	-0.0326
48	100	Unbiased-100krad	0.5835	0.5584	-0.0251
49	100	Unbiased-100krad	0.586	0.5509	-0.0351
50	105	Biased-100krad	0.586	0.5434	-0.0426
51	105	Biased-100krad	0.581	0.5459	-0.0351
52	105	Biased-100krad	0.5835	0.5409	-0.0426
53	105	Biased-100krad	0.5835	0.5484	-0.0351
54	105	Biased-100krad	0.586	0.5434	-0.0426

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.586	0.591	0.5935	0.0043301	0.586	0.59017	0.5935	0.0038188	-0.0025	-0.00083333	0	0.0014434
30	0.5835	0.588	0.5985	0.0059687	0.5559	0.56192	0.5735	0.0067972	-0.0276	-0.02608	-0.025	0.0013882
35	0.5835	0.5845	0.586	0.0013693	0.5559	0.5574	0.5609	0.0022361	-0.0301	-0.0271	-0.0251	0.0020917
50	0.5835	0.5865	0.596	0.0054199	0.5434	0.5479	0.5559	0.0048088	-0.0401	-0.0386	-0.0376	0.0013693
55	0.5785	0.5825	0.586	0.0028504	0.5359	0.5399	0.5459	0.0037914	-0.0476	-0.0426	-0.0376	0.0039528
100	0.581	0.5825	0.586	0.0022361	0.5484	0.5519	0.5584	0.0041833	-0.0351	-0.0306	-0.0251	0.0041079
105	0.581	0.584	0.586	0.0020917	0.5409	0.5444	0.5484	0.0028504	-0.0426	-0.0396	-0.0351	0.0041079

Device Test: 30.3 _PWRGD|VOL/PWRGD3/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW





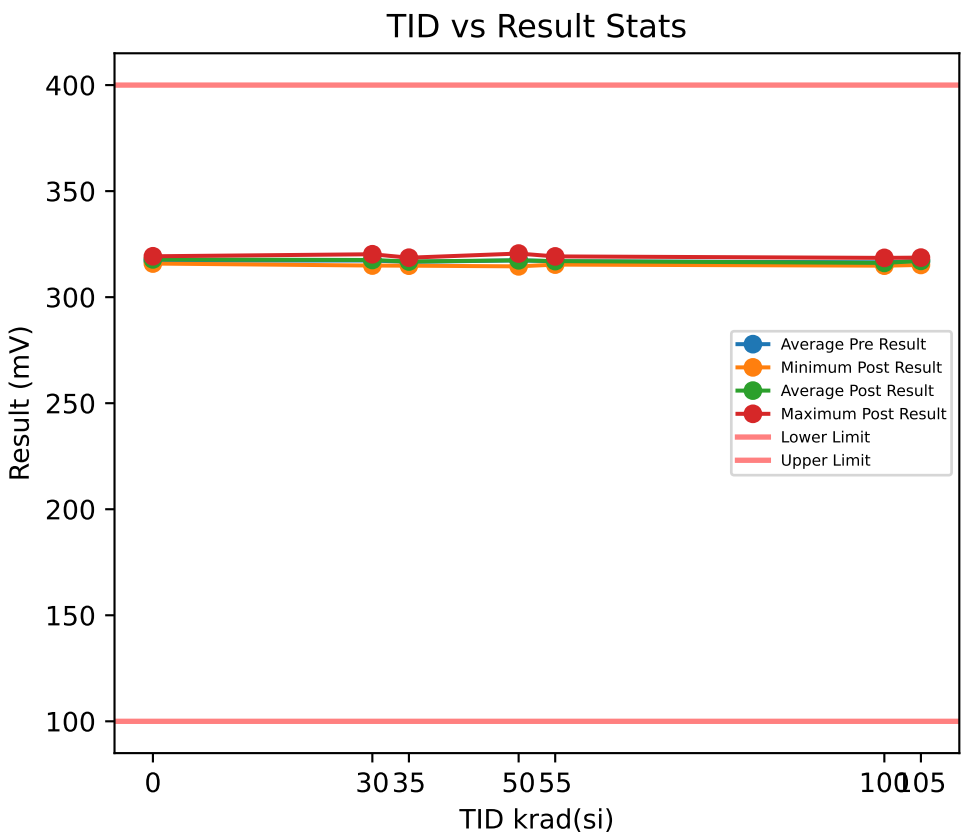
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

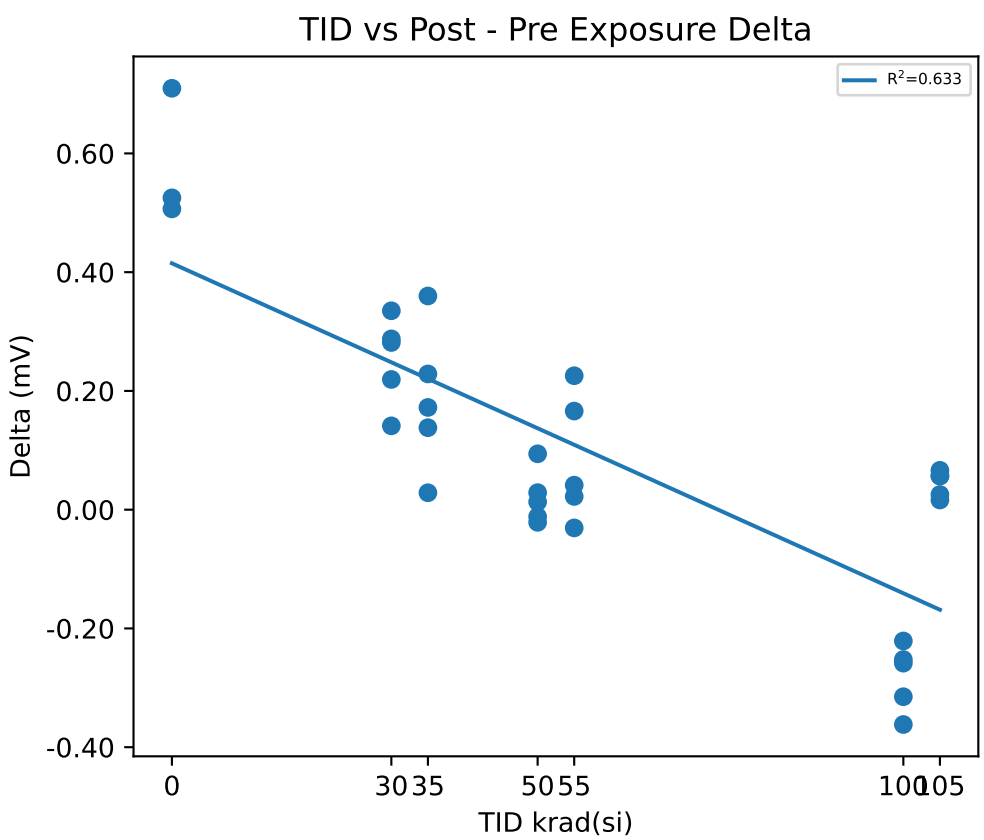
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	316.68	317.45	0.776
2	0	CU2	313.98	314.77	0.7885
3	0	CU3	316.75	317.45	0.7042
11	30	Unbiased-30krad	314.12	314.67	0.5512
12	30	Unbiased-30krad	315.96	316.39	0.4325
13	30	Unbiased-30krad	313.95	314.38	0.4294
14	30	Unbiased-30krad	316.85	317.37	0.5137
15	30	Unbiased-30krad	318.72	319.27	0.5511
16	35	Biased-30krad	317.34	317.89	0.548
17	35	Biased-30krad	315.07	315.57	0.4981
18	35	Biased-30krad	316.19	316.66	0.4669
19	35	Biased-30krad	313.47	313.94	0.4731
20	35	Biased-30krad	314.28	314.66	0.3794
30	50	Unbiased-50krad	315.39	315.7	0.3107
31	50	Unbiased-50krad	313.87	314.2	0.3263
32	50	Unbiased-50krad	317.48	317.75	0.2701
33	50	Unbiased-50krad	316.4	316.57	0.1733
34	50	Unbiased-50krad	319.48	319.76	0.2794
40	55	Biased-50krad	313.88	314.12	0.239
41	55	Biased-50krad	314.88	315.26	0.3763
42	55	Biased-50krad	317.27	317.67	0.395
43	55	Biased-50krad	316.92	317.32	0.395
44	55	Biased-50krad	314.24	314.56	0.3201
45	100	Unbiased-100krad	314.42	314.32	-0.0984
46	100	Unbiased-100krad	315.85	315.89	0.0422
47	100	Unbiased-100krad	313.83	313.8	-0.0297
48	100	Unbiased-100krad	315.24	315.26	0.0141
49	100	Unbiased-100krad	317.65	317.68	0.0234
50	105	Biased-100krad	317.33	317.69	0.3638
51	105	Biased-100krad	314.55	314.88	0.3295
52	105	Biased-100krad	316.29	316.68	0.3888
53	105	Biased-100krad	314.41	314.73	0.3232
54	105	Biased-100krad	318.09	318.35	0.2576

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	313.98	315.8	316.75	1.5762	314.77	316.56	317.45	1.5479	0.7042	0.75623	0.7885	0.045494
30	313.95	315.92	318.72	1.9892	314.38	316.41	319.27	2.0152	0.4294	0.49558	0.5512	0.060958
35	313.47	315.27	317.34	1.5351	313.94	315.74	317.89	1.5745	0.3794	0.4731	0.548	0.061346
50	313.87	316.52	319.48	2.1215	314.2	316.8	319.76	2.1039	0.1733	0.27196	0.3263	0.059679
55	313.88	315.44	317.27	1.5602	314.12	315.79	317.67	1.6157	0.239	0.34508	0.395	0.066775
100	313.83	315.4	317.65	1.4762	313.8	315.39	317.68	1.5128	-0.0984	-0.00968	0.0422	0.056177
105	314.41	316.13	318.09	1.6406	314.73	316.47	318.35	1.6292	0.2576	0.33258	0.3888	0.049636

Device Test: 30.4 _PWRGD|VOL/PWRGD4/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW





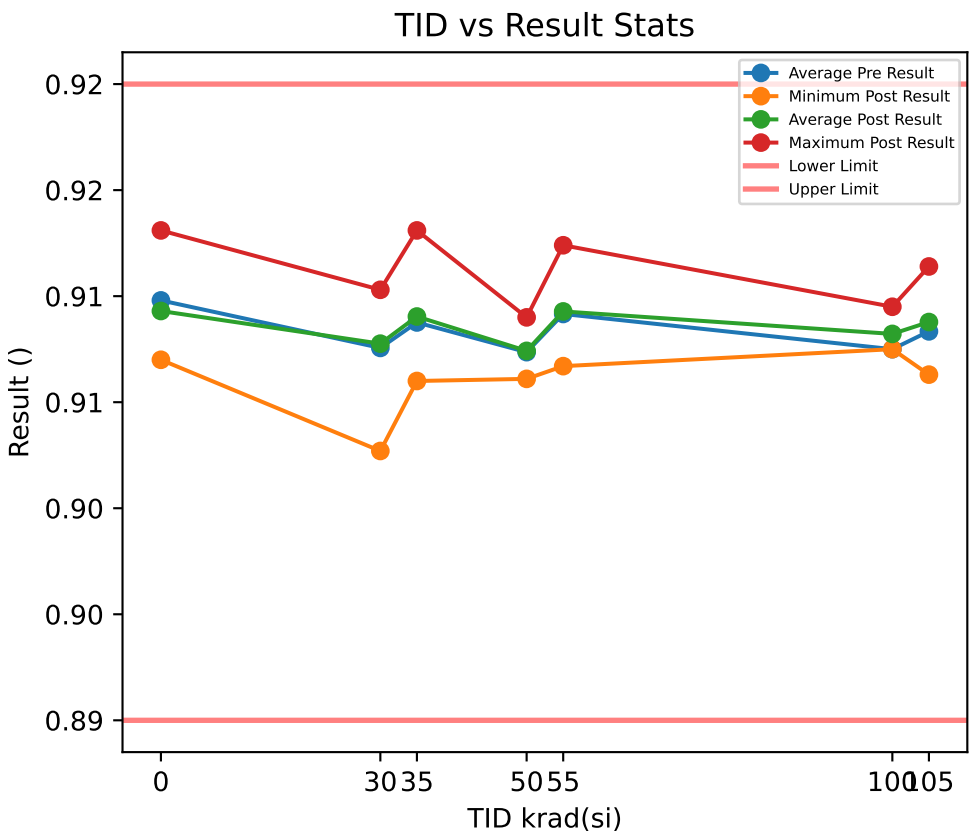
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

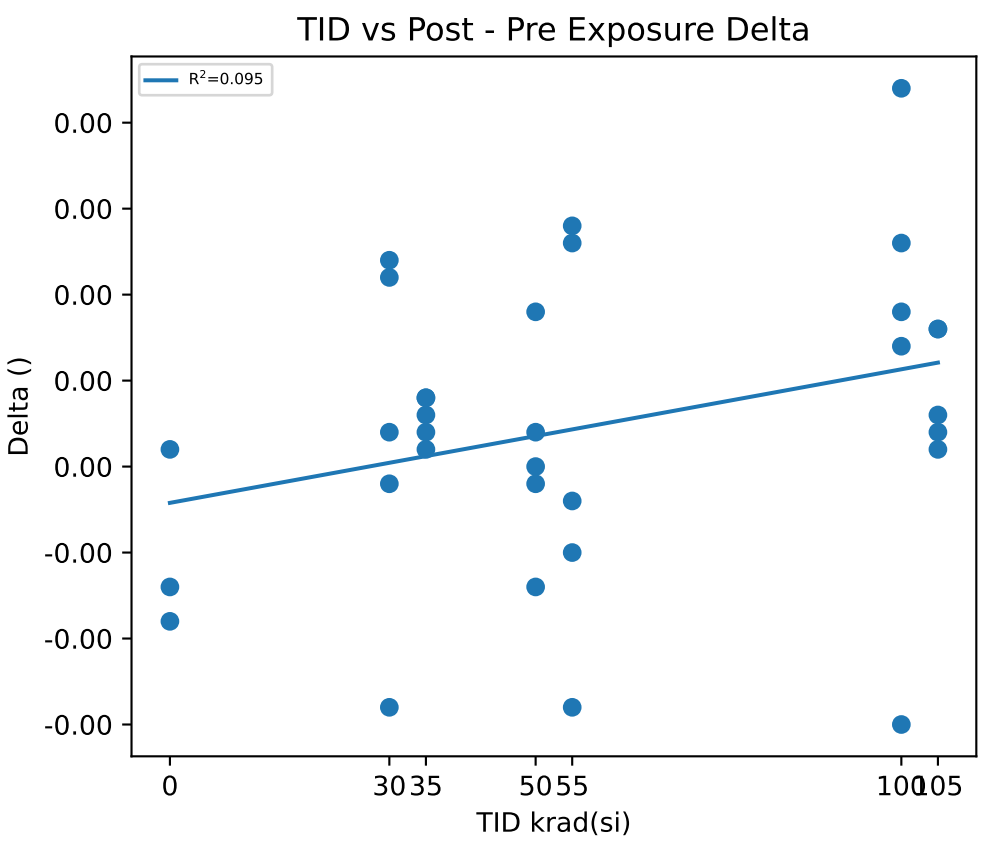
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	318.57	319.28	0.7097
2	0	CU2	315.32	315.85	0.5252
3	0	CU3	317.79	318.29	0.5066
11	30	Unbiased-30krad	316.09	316.37	0.2816
12	30	Unbiased-30krad	317.84	317.99	0.1412
13	30	Unbiased-30krad	314.62	314.91	0.2877
14	30	Unbiased-30krad	317.93	318.15	0.2193
15	30	Unbiased-30krad	319.9	320.23	0.335
16	35	Biased-30krad	318.25	318.61	0.3599
17	35	Biased-30krad	317.05	317.28	0.2286
18	35	Biased-30krad	318.04	318.18	0.1381
19	35	Biased-30krad	314.67	314.85	0.1722
20	35	Biased-30krad	315.14	315.17	0.0285
30	50	Unbiased-50krad	316.96	316.99	0.0287
31	50	Unbiased-50krad	314.43	314.52	0.0941
32	50	Unbiased-50krad	317.91	317.92	0.0131
33	50	Unbiased-50krad	316.9	316.88	-0.0213
34	50	Unbiased-50krad	320.57	320.56	-0.0117
40	55	Biased-50krad	315.33	315.35	0.0223
41	55	Biased-50krad	316.59	316.75	0.1661
42	55	Biased-50krad	318.99	319.22	0.2256
43	55	Biased-50krad	317.71	317.75	0.0413
44	55	Biased-50krad	316	315.97	-0.0307
45	100	Unbiased-100krad	315.24	314.92	-0.315
46	100	Unbiased-100krad	316.79	316.57	-0.2211
47	100	Unbiased-100krad	315.21	314.85	-0.3618
48	100	Unbiased-100krad	316.15	315.9	-0.2524
49	100	Unbiased-100krad	318.78	318.52	-0.2585
50	105	Biased-100krad	318.37	318.44	0.0663
51	105	Biased-100krad	315.67	315.7	0.0255
52	105	Biased-100krad	317.48	317.54	0.0569
53	105	Biased-100krad	315.13	315.19	0.0567
54	105	Biased-100krad	318.63	318.65	0.0163

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	315.32	317.23	318.57	1.6936	315.85	317.81	319.28	1.7658	0.5066	0.5805	0.7097	0.11228
30	314.62	317.28	319.9	2.0058	314.91	317.53	320.23	2.0076	0.1412	0.25296	0.335	0.074801
35	314.67	316.63	318.25	1.6462	314.85	316.82	318.61	1.7239	0.0285	0.18546	0.3599	0.1218
50	314.43	317.36	320.57	2.2122	314.52	317.38	320.56	2.1777	-0.0213	0.02058	0.0941	0.045615
55	315.33	316.92	318.99	1.4494	315.35	317.01	319.22	1.5264	-0.0307	0.08492	0.2256	0.10674
100	315.21	316.43	318.78	1.4701	314.85	316.15	318.52	1.5057	-0.3618	-0.28176	-0.2211	0.056111
105	315.13	317.06	318.63	1.5806	315.19	317.1	318.65	1.5795	0.0163	0.04434	0.0663	0.021988

Device Test: 30.5 _PWRGD|FallingFault/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





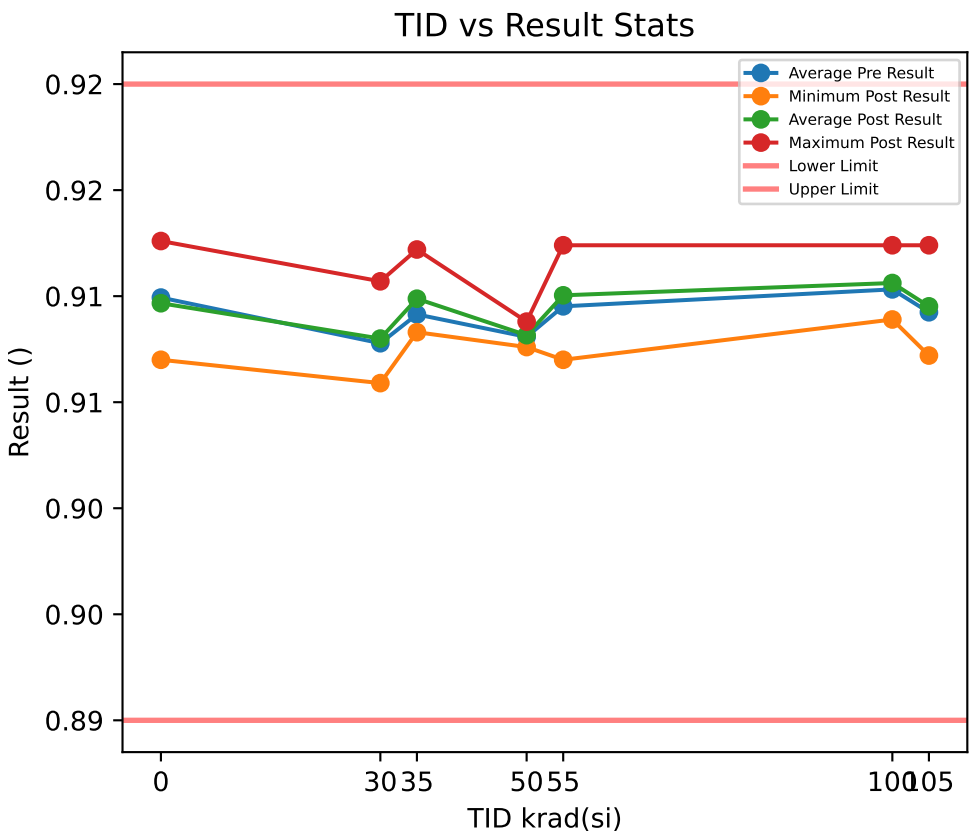
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

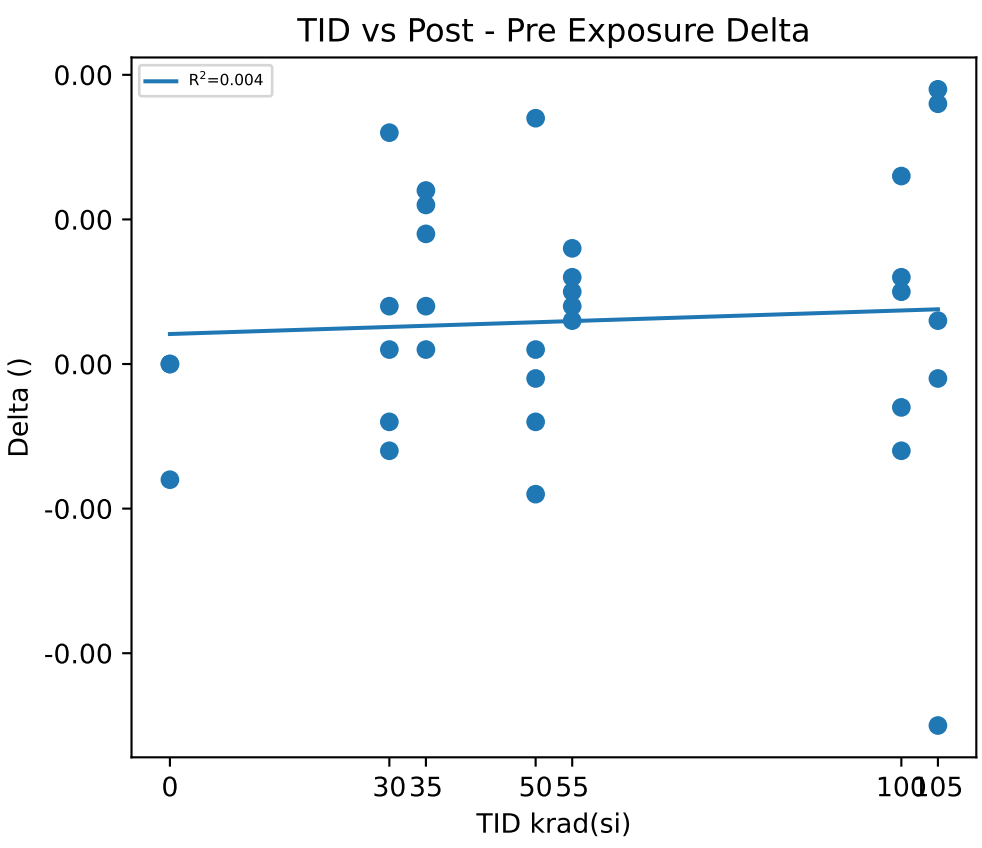
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9069	0.907	0.0001
2	0	CU2	0.9138	0.9131	-0.0007
3	0	CU3	0.9087	0.9078	-0.0009
11	30	Unbiased-30krad	0.908	0.9092	0.0012
12	30	Unbiased-30krad	0.9092	0.9103	0.0011
13	30	Unbiased-30krad	0.9041	0.9027	-0.0014
14	30	Unbiased-30krad	0.9094	0.9096	0.0002
15	30	Unbiased-30krad	0.9071	0.907	-0.0001
16	35	Biased-30krad	0.909	0.9091	0.0001
17	35	Biased-30krad	0.908	0.9082	0.0002
18	35	Biased-30krad	0.9127	0.9131	0.0004
19	35	Biased-30krad	0.9056	0.906	0.0004
20	35	Biased-30krad	0.9085	0.9088	0.0003
30	50	Unbiased-50krad	0.9075	0.9074	-0.0001
31	50	Unbiased-50krad	0.9073	0.9073	0
32	50	Unbiased-50krad	0.9064	0.9073	0.0009
33	50	Unbiased-50krad	0.9059	0.9061	0.0002
34	50	Unbiased-50krad	0.9097	0.909	-0.0007
40	55	Biased-50krad	0.9085	0.9071	-0.0014
41	55	Biased-50krad	0.9129	0.9124	-0.0005
42	55	Biased-50krad	0.9097	0.9095	-0.0002
43	55	Biased-50krad	0.9094	0.9107	0.0013
44	55	Biased-50krad	0.9053	0.9067	0.0014
45	100	Unbiased-100krad	0.9067	0.9076	0.0009
46	100	Unbiased-100krad	0.9062	0.9075	0.0013
47	100	Unbiased-100krad	0.9073	0.9095	0.0022
48	100	Unbiased-100krad	0.908	0.9087	0.0007
49	100	Unbiased-100krad	0.9093	0.9078	-0.0015
50	105	Biased-100krad	0.9075	0.9083	0.0008
51	105	Biased-100krad	0.9097	0.9099	0.0002
52	105	Biased-100krad	0.906	0.9063	0.0003
53	105	Biased-100krad	0.9106	0.9114	0.0008
54	105	Biased-100krad	0.9079	0.908	0.0001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9069	0.9098	0.9138	0.0035791	0.907	0.9093	0.9131	0.0033151	-0.0009	-0.0005	0.0001	0.00052915
30	0.9041	0.90756	0.9094	0.0021478	0.9027	0.90776	0.9103	0.0030859	-0.0014	0.0002	0.0012	0.0010559
35	0.9056	0.90876	0.9127	0.0025599	0.906	0.90904	0.9131	0.0025735	0.0001	0.00028	0.0004	0.00013038
50	0.9059	0.90736	0.9097	0.0014622	0.9061	0.90742	0.909	0.001033	-0.0007	6e-05	0.0009	0.00057706
55	0.9053	0.90916	0.9129	0.0027236	0.9067	0.90928	0.9124	0.0024087	-0.0014	0.00012	0.0014	0.0012071
100	0.9062	0.9075	0.9093	0.0012104	0.9075	0.90822	0.9095	0.00085849	-0.0015	0.00072	0.0022	0.0013682
105	0.906	0.90834	0.9106	0.0018257	0.9063	0.90878	0.9114	0.0019435	0.0001	0.00044	0.0008	0.00033615

Device Test: 30.6 _PWRGD|FallingFault/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





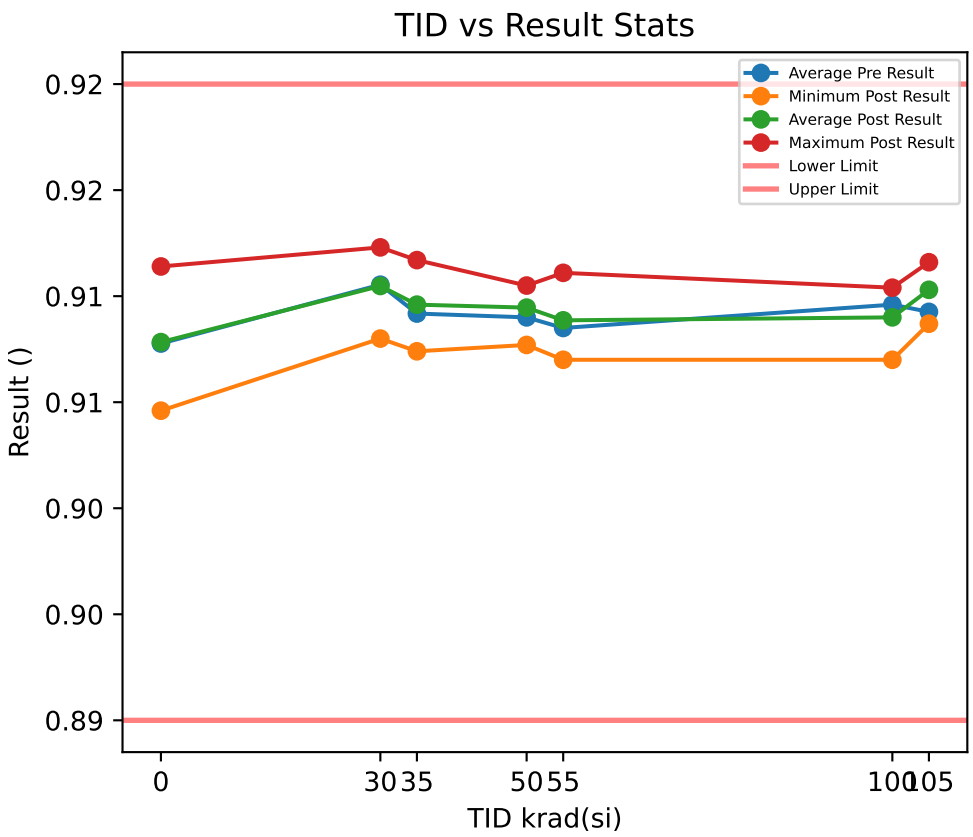
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

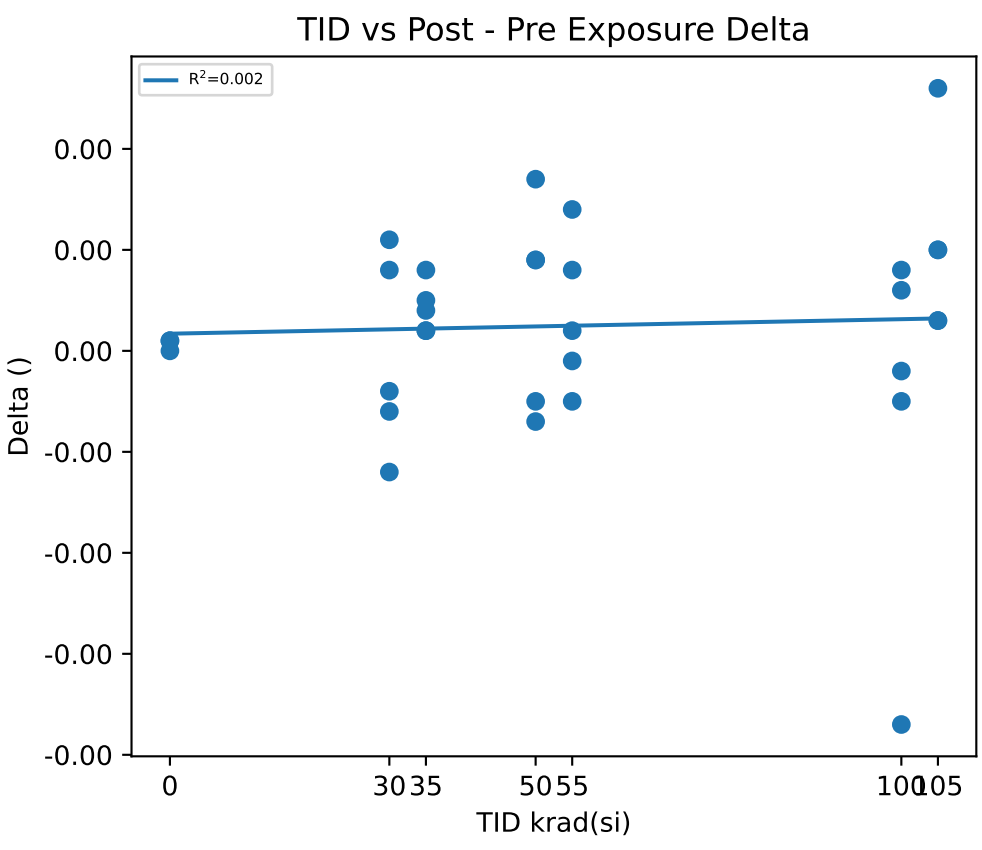
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9134	0.9126	-0.0008
2	0	CU2	0.9094	0.9094	0
3	0	CU3	0.907	0.907	0
11	30	Unbiased-30krad	0.9063	0.9059	-0.0004
12	30	Unbiased-30krad	0.9091	0.9085	-0.0006
13	30	Unbiased-30krad	0.9103	0.9107	0.0004
14	30	Unbiased-30krad	0.9065	0.9066	0.0001
15	30	Unbiased-30krad	0.9067	0.9083	0.0016
16	35	Biased-30krad	0.9089	0.9098	0.0009
17	35	Biased-30krad	0.9083	0.9084	0.0001
18	35	Biased-30krad	0.9079	0.9083	0.0004
19	35	Biased-30krad	0.911	0.9122	0.0012
20	35	Biased-30krad	0.9096	0.9107	0.0011
30	50	Unbiased-50krad	0.9077	0.9076	-0.0001
31	50	Unbiased-50krad	0.9085	0.9076	-0.0009
32	50	Unbiased-50krad	0.9071	0.9088	0.0017
33	50	Unbiased-50krad	0.9085	0.9081	-0.0004
34	50	Unbiased-50krad	0.9086	0.9087	0.0001
40	55	Biased-50krad	0.9119	0.9124	0.0005
41	55	Biased-50krad	0.9107	0.9111	0.0004
42	55	Biased-50krad	0.9062	0.907	0.0008
43	55	Biased-50krad	0.9093	0.9096	0.0003
44	55	Biased-50krad	0.9095	0.9101	0.0006
45	100	Unbiased-100krad	0.913	0.9124	-0.0006
46	100	Unbiased-100krad	0.9083	0.9089	0.0006
47	100	Unbiased-100krad	0.9096	0.9101	0.0005
48	100	Unbiased-100krad	0.9114	0.9111	-0.0003
49	100	Unbiased-100krad	0.9093	0.9106	0.0013
50	105	Biased-100krad	0.9082	0.9081	-0.0001
51	105	Biased-100krad	0.9079	0.9097	0.0018
52	105	Biased-100krad	0.9083	0.9102	0.0019
53	105	Biased-100krad	0.9097	0.9072	-0.0025
54	105	Biased-100krad	0.9121	0.9124	0.0003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.907	0.90993	0.9134	0.0032332	0.907	0.90967	0.9126	0.0028095	-0.0008	-0.00026667	0	0.00046188
30	0.9063	0.90778	0.9103	0.0018089	0.9059	0.908	0.9107	0.0018708	-0.0006	0.00022	0.0016	0.00086718
35	0.9079	0.90914	0.911	0.0012219	0.9083	0.90988	0.9122	0.0016392	0.0001	0.00074	0.0012	0.00047223
50	0.9071	0.90808	0.9086	0.00065727	0.9076	0.90816	0.9088	0.00057706	-0.0009	8e-05	0.0017	0.00098082
55	0.9062	0.90952	0.9119	0.0021288	0.907	0.91004	0.9124	0.0020082	0.0003	0.00052	0.0008	0.00019235
100	0.9083	0.91032	0.913	0.00187	0.9089	0.91062	0.9124	0.0012872	-0.0006	0.0003	0.0013	0.00075829
105	0.9079	0.90924	0.9121	0.001743	0.9072	0.90952	0.9124	0.0020117	-0.0025	0.00028	0.0019	0.0017894

Device Test: 30.7 _PWRGD|FallingFault/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





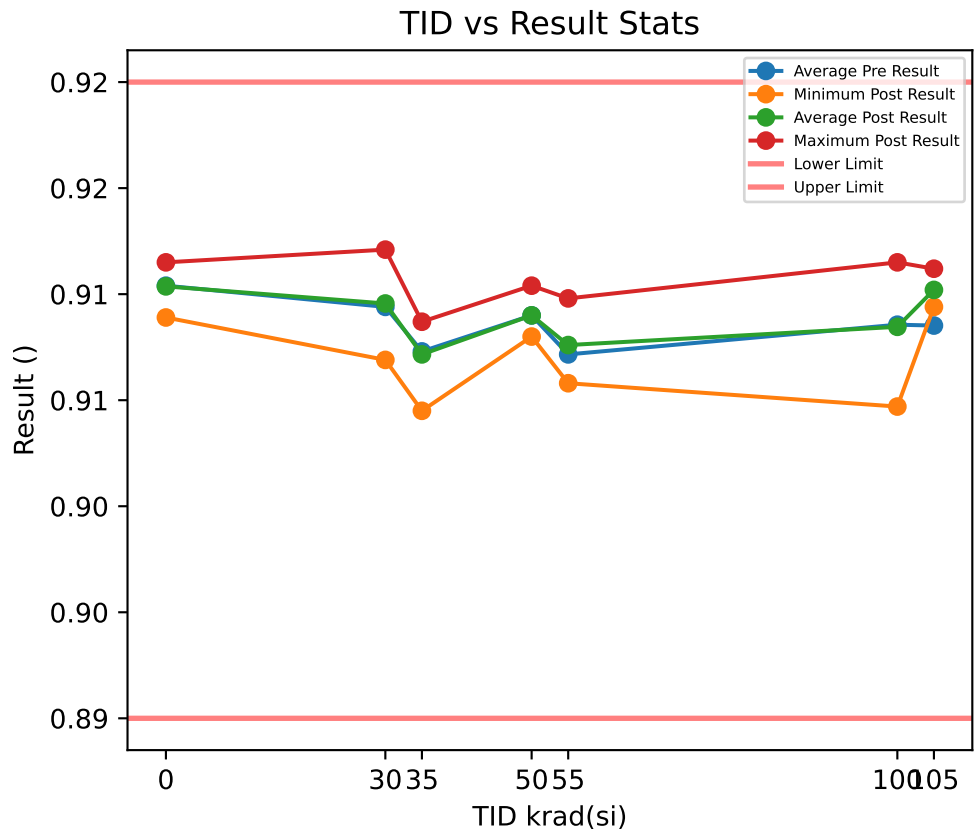
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

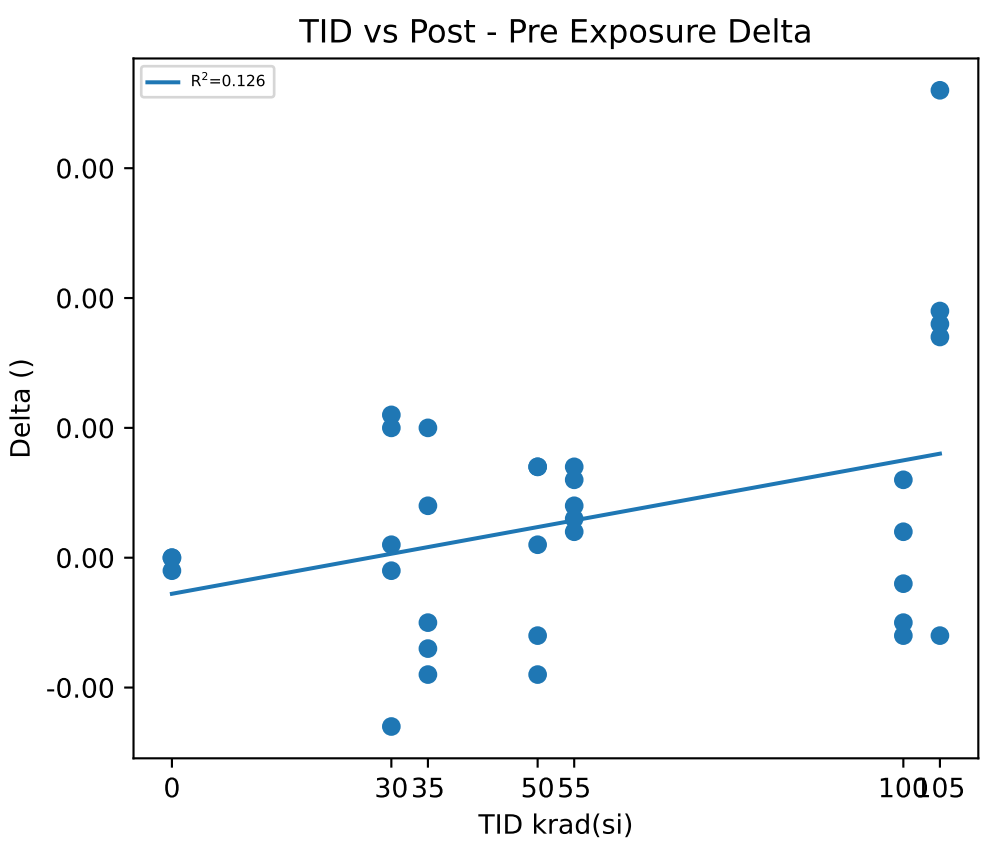
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9113	0.9114	0.0001
2	0	CU2	0.9045	0.9046	0.0001
3	0	CU3	0.9075	0.9075	0
11	30	Unbiased-30krad	0.912	0.9116	-0.0004
12	30	Unbiased-30krad	0.9112	0.9123	0.0011
13	30	Unbiased-30krad	0.9126	0.9114	-0.0012
14	30	Unbiased-30krad	0.9086	0.908	-0.0006
15	30	Unbiased-30krad	0.9083	0.9091	0.0008
16	35	Biased-30krad	0.9098	0.9106	0.0008
17	35	Biased-30krad	0.9091	0.9093	0.0002
18	35	Biased-30krad	0.9086	0.909	0.0004
19	35	Biased-30krad	0.9112	0.9117	0.0005
20	35	Biased-30krad	0.9072	0.9074	0.0002
30	50	Unbiased-50krad	0.9068	0.9077	0.0009
31	50	Unbiased-50krad	0.9075	0.9092	0.0017
32	50	Unbiased-50krad	0.9096	0.9105	0.0009
33	50	Unbiased-50krad	0.9104	0.9099	-0.0005
34	50	Unbiased-50krad	0.9107	0.91	-0.0007
40	55	Biased-50krad	0.9091	0.9093	0.0002
41	55	Biased-50krad	0.9089	0.9084	-0.0005
42	55	Biased-50krad	0.9103	0.9111	0.0008
43	55	Biased-50krad	0.9071	0.9085	0.0014
44	55	Biased-50krad	0.9071	0.907	-0.0001
45	100	Unbiased-100krad	0.9073	0.9081	0.0008
46	100	Unbiased-100krad	0.91	0.9098	-0.0002
47	100	Unbiased-100krad	0.9075	0.907	-0.0005
48	100	Unbiased-100krad	0.9098	0.9104	0.0006
49	100	Unbiased-100krad	0.9134	0.9097	-0.0037
50	105	Biased-100krad	0.9079	0.9105	0.0026
51	105	Biased-100krad	0.9113	0.9116	0.0003
52	105	Biased-100krad	0.9092	0.9102	0.001
53	105	Biased-100krad	0.9077	0.9087	0.001
54	105	Biased-100krad	0.9102	0.9105	0.0003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9045	0.90777	0.9113	0.0034078	0.9046	0.90783	0.9114	0.0034122	0	6.6667e-05	0.0001	5.7735e-05
30	0.9083	0.91054	0.9126	0.0019743	0.908	0.91048	0.9123	0.0018349	-0.0012	-6e-05	0.0011	0.00097365
35	0.9072	0.90918	0.9112	0.0014772	0.9074	0.9096	0.9117	0.0016355	0.0002	0.00042	0.0008	0.000249
50	0.9068	0.909	0.9107	0.0017536	0.9077	0.90946	0.9105	0.0010877	-0.0007	0.00046	0.0017	0.0010237
55	0.9071	0.9085	0.9103	0.0013856	0.907	0.90886	0.9111	0.001501	-0.0005	0.00036	0.0014	0.00075033
100	0.9073	0.9096	0.9134	0.0024668	0.907	0.909	0.9104	0.0014053	-0.0037	-0.0006	0.0008	0.0018152
105	0.9077	0.90926	0.9113	0.0015274	0.9087	0.9103	0.9116	0.0010416	0.0003	0.00104	0.0026	0.00093968

Device Test: 30.8 _PWRGD|FallingFault/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





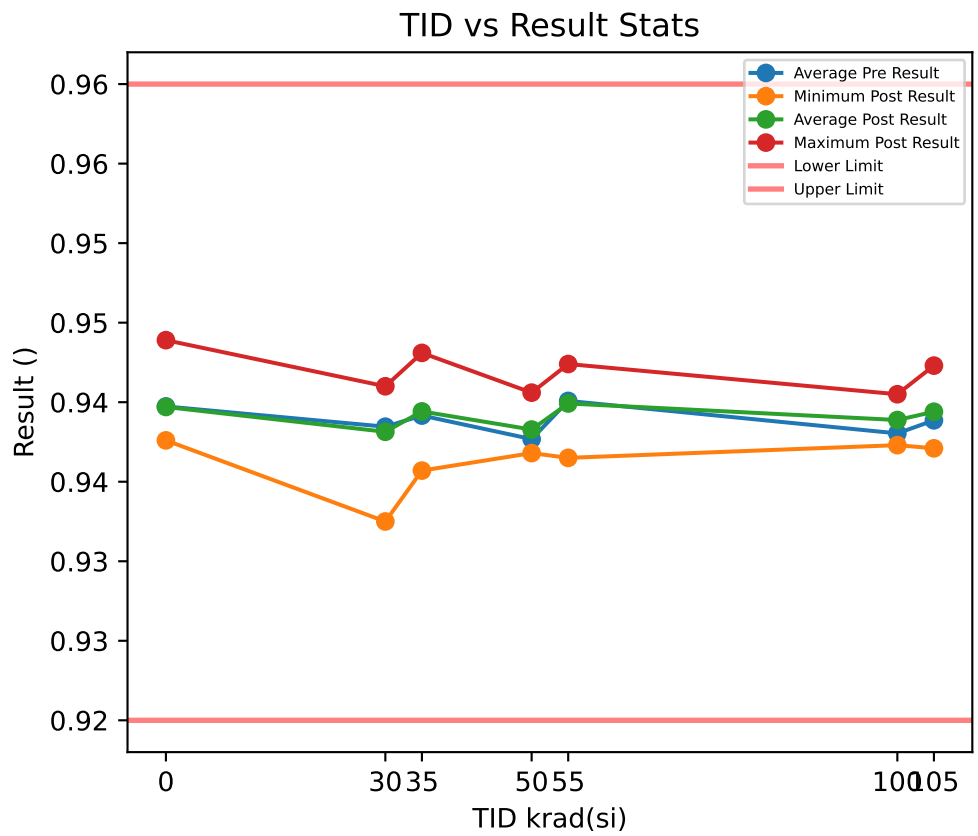
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

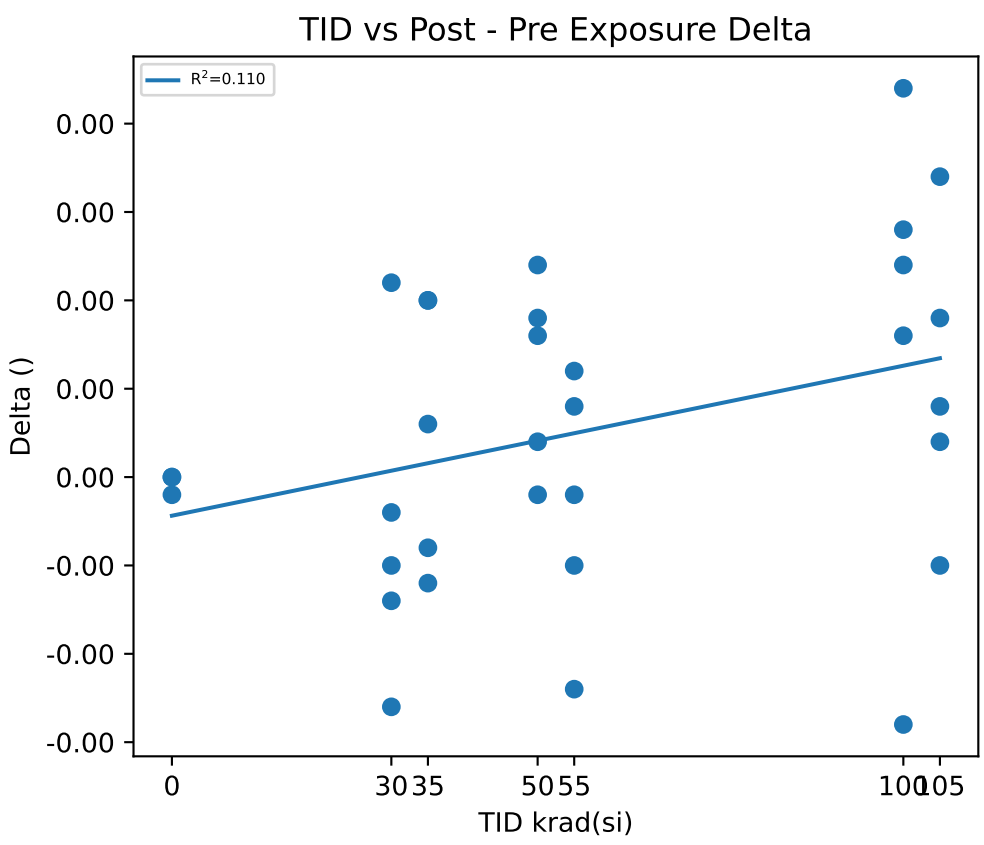
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9115	0.9115	0
2	0	CU2	0.9089	0.9089	0
3	0	CU3	0.9108	0.9107	-0.0001
11	30	Unbiased-30krad	0.9099	0.9086	-0.0013
12	30	Unbiased-30krad	0.9068	0.9069	0.0001
13	30	Unbiased-30krad	0.908	0.9091	0.0011
14	30	Unbiased-30krad	0.9111	0.9121	0.001
15	30	Unbiased-30krad	0.9112	0.9111	-0.0001
16	35	Biased-30krad	0.9054	0.9045	-0.0009
17	35	Biased-30krad	0.9072	0.9065	-0.0007
18	35	Biased-30krad	0.9076	0.908	0.0004
19	35	Biased-30krad	0.9092	0.9087	-0.0005
20	35	Biased-30krad	0.9071	0.9081	0.001
30	50	Unbiased-50krad	0.9081	0.9088	0.0007
31	50	Unbiased-50krad	0.9073	0.908	0.0007
32	50	Unbiased-50krad	0.9104	0.9095	-0.0009
33	50	Unbiased-50krad	0.9089	0.9083	-0.0006
34	50	Unbiased-50krad	0.9103	0.9104	0.0001
40	55	Biased-50krad	0.9083	0.9085	0.0002
41	55	Biased-50krad	0.9095	0.9098	0.0003
42	55	Biased-50krad	0.9067	0.9074	0.0007
43	55	Biased-50krad	0.9061	0.9065	0.0004
44	55	Biased-50krad	0.9052	0.9058	0.0006
45	100	Unbiased-100krad	0.9113	0.9115	0.0002
46	100	Unbiased-100krad	0.9109	0.9115	0.0006
47	100	Unbiased-100krad	0.9082	0.9077	-0.0005
48	100	Unbiased-100krad	0.9049	0.9047	-0.0002
49	100	Unbiased-100krad	0.9075	0.9069	-0.0006
50	105	Biased-100krad	0.9079	0.9096	0.0017
51	105	Biased-100krad	0.91	0.9094	-0.0006
52	105	Biased-100krad	0.9078	0.9097	0.0019
53	105	Biased-100krad	0.9094	0.9112	0.0018
54	105	Biased-100krad	0.9075	0.9111	0.0036

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9089	0.9104	0.9115	0.0013454	0.9089	0.91037	0.9115	0.0013317	-0.0001	-3.3333e-05	0	5.7735e-05
30	0.9068	0.9094	0.9112	0.0019429	0.9069	0.90956	0.9121	0.0020635	-0.0013	0.00016	0.0011	0.00097365
35	0.9054	0.9073	0.9092	0.0013565	0.9045	0.90716	0.9087	0.0016935	-0.0009	-0.00014	0.001	0.00080808
50	0.9073	0.909	0.9104	0.0013565	0.908	0.909	0.9104	0.00096695	-0.0009	0	0.0007	0.00073485
55	0.9052	0.90716	0.9095	0.0017286	0.9058	0.9076	0.9098	0.0015922	0.0002	0.00044	0.0007	0.00020736
100	0.9049	0.90856	0.9113	0.0026283	0.9047	0.90846	0.9115	0.0029846	-0.0006	-0.0001	0.0006	0.0005
105	0.9075	0.90852	0.91	0.0011077	0.9094	0.9102	0.9112	0.00087464	-0.0006	0.00168	0.0036	0.0014957

Device Test: 30.9 _PWRGD|RisingGood/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





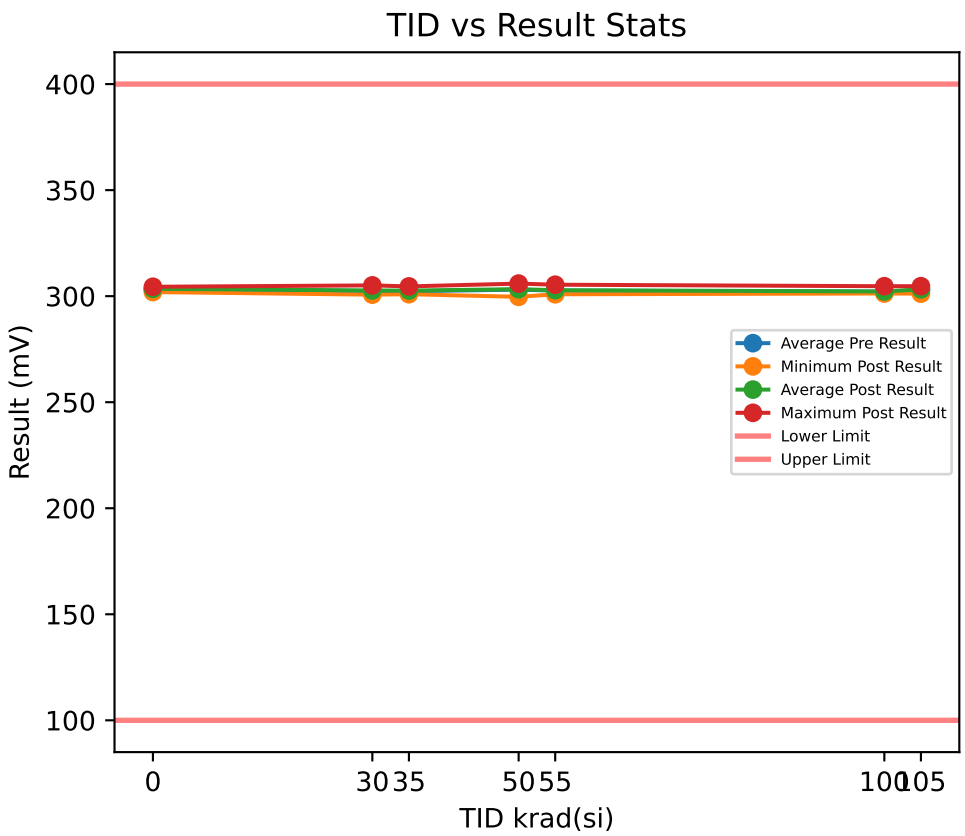
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

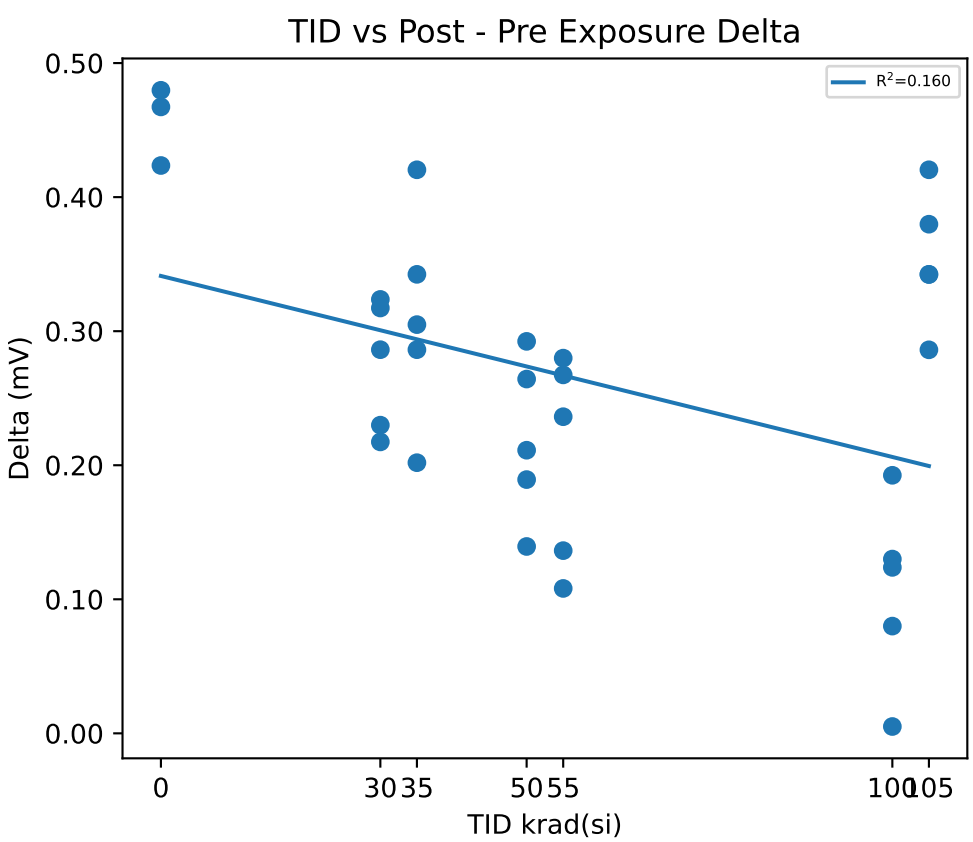
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9376	0.9376	0
2	0	CU2	0.9439	0.9439	0
3	0	CU3	0.9377	0.9376	-0.0001
11	30	Unbiased-30krad	0.9405	0.94	-0.0005
12	30	Unbiased-30krad	0.9399	0.941	0.0011
13	30	Unbiased-30krad	0.9338	0.9325	-0.0013
14	30	Unbiased-30krad	0.9411	0.9404	-0.0007
15	30	Unbiased-30krad	0.937	0.9368	-0.0002
16	35	Biased-30krad	0.9389	0.9399	0.001
17	35	Biased-30krad	0.9379	0.9389	0.001
18	35	Biased-30krad	0.9435	0.9431	-0.0004
19	35	Biased-30krad	0.9363	0.9357	-0.0006
20	35	Biased-30krad	0.9392	0.9395	0.0003
30	50	Unbiased-50krad	0.9373	0.9381	0.0008
31	50	Unbiased-50krad	0.9372	0.9371	-0.0001
32	50	Unbiased-50krad	0.9379	0.9388	0.0009
33	50	Unbiased-50krad	0.9356	0.9368	0.0012
34	50	Unbiased-50krad	0.9404	0.9406	0.0002
40	55	Biased-50krad	0.9392	0.938	-0.0012
41	55	Biased-50krad	0.9429	0.9424	-0.0005
42	55	Biased-50krad	0.9413	0.9412	-0.0001
43	55	Biased-50krad	0.9411	0.9415	0.0004
44	55	Biased-50krad	0.9359	0.9365	0.0006
45	100	Unbiased-100krad	0.9373	0.9385	0.0012
46	100	Unbiased-100krad	0.9359	0.9373	0.0014
47	100	Unbiased-100krad	0.9381	0.9403	0.0022
48	100	Unbiased-100krad	0.9397	0.9405	0.0008
49	100	Unbiased-100krad	0.9392	0.9378	-0.0014
50	105	Biased-100krad	0.9373	0.939	0.0017
51	105	Biased-100krad	0.9403	0.9398	-0.0005
52	105	Biased-100krad	0.9367	0.9371	0.0004
53	105	Biased-100krad	0.9414	0.9423	0.0009
54	105	Biased-100krad	0.9386	0.9388	0.0002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9376	0.93973	0.9439	0.0036088	0.9376	0.9397	0.9439	0.0036373	-0.0001	-3.3333e-05	0	5.7735e-05
30	0.9338	0.93846	0.9411	0.0030435	0.9325	0.93814	0.941	0.003548	-0.0013	-0.00032	0.0011	0.00088994
35	0.9363	0.93916	0.9435	0.0026773	0.9357	0.93942	0.9431	0.0026405	-0.0006	0.00026	0.001	0.00075366
50	0.9356	0.93768	0.9404	0.0017427	0.9368	0.93828	0.9406	0.0015222	-0.0001	0.0006	0.0012	0.00053385
55	0.9359	0.94008	0.9429	0.0026799	0.9365	0.93992	0.9424	0.0025332	-0.0012	-0.00016	0.0006	0.00072319
100	0.9359	0.93804	0.9397	0.0015192	0.9373	0.93888	0.9405	0.0014533	-0.0014	0.00084	0.0022	0.001352
105	0.9367	0.93886	0.9414	0.0019807	0.9371	0.9394	0.9423	0.001896	-0.0005	0.00054	0.0017	0.00082037

Device Test: 31.1 _PWRGD|VOL/PWRGD1/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW





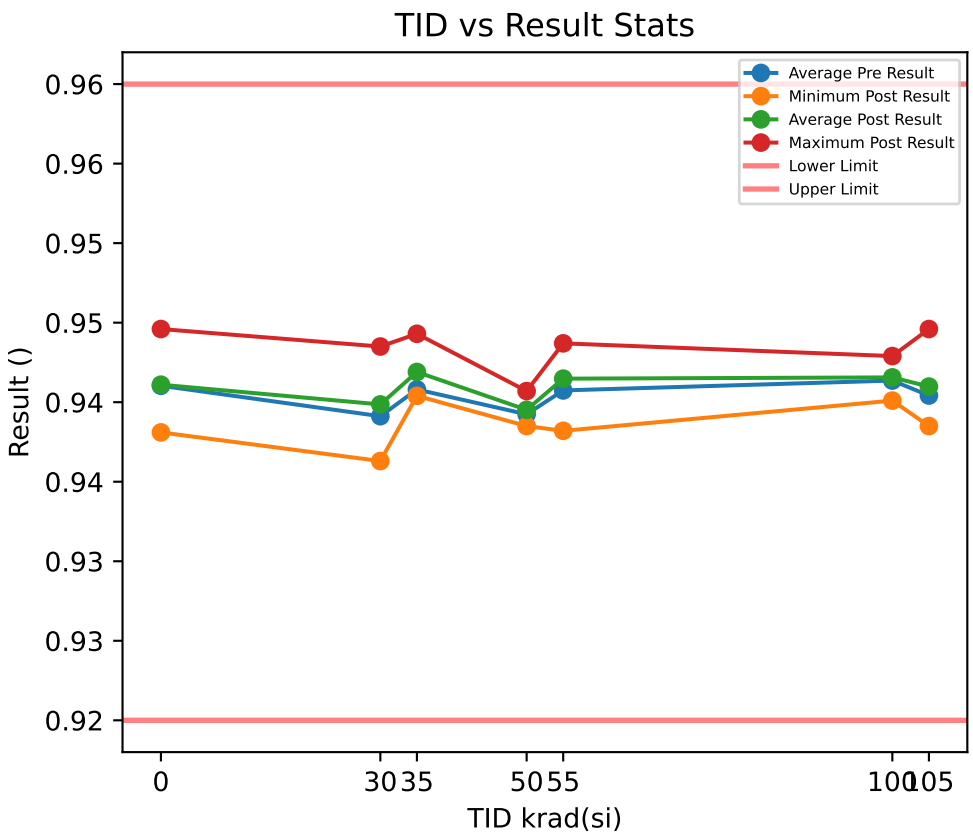
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

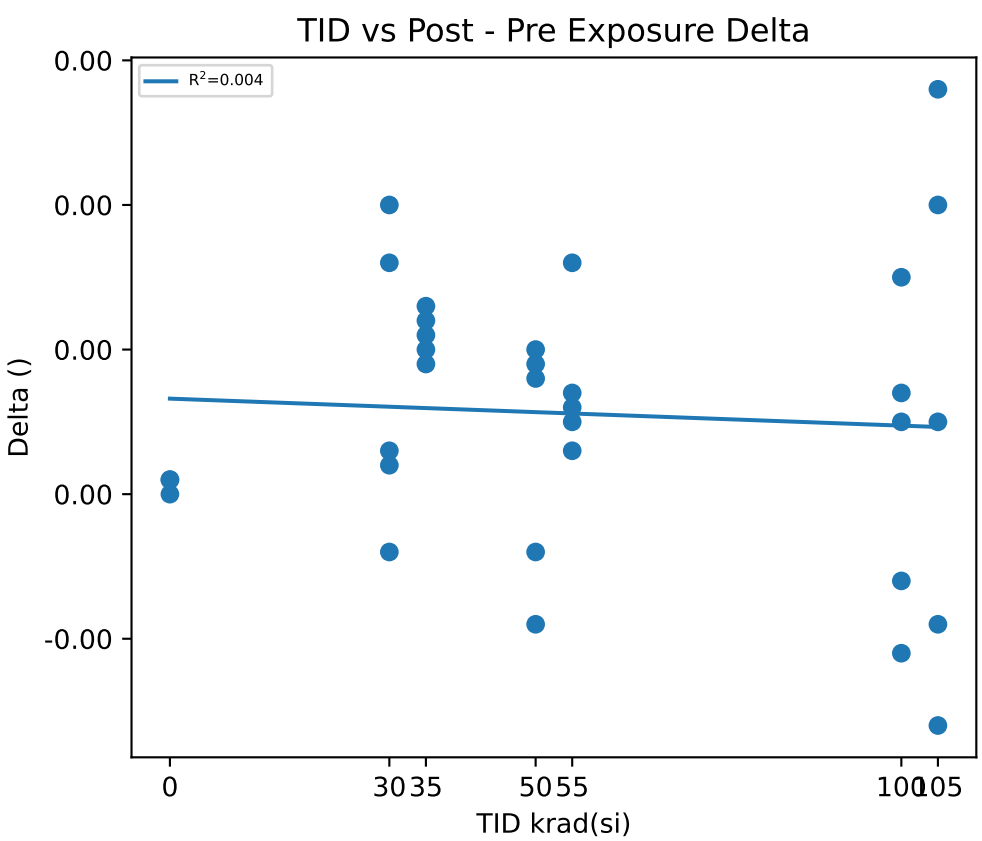
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	303.95	304.43	0.4797
2	0	CU2	301.46	301.92	0.4673
3	0	CU3	303.6	304.02	0.4236
11	30	Unbiased-30krad	300.49	300.71	0.2174
12	30	Unbiased-30krad	303.37	303.65	0.2862
13	30	Unbiased-30krad	300.49	300.72	0.2299
14	30	Unbiased-30krad	302.98	303.31	0.3237
15	30	Unbiased-30krad	304.76	305.08	0.3173
16	35	Biased-30krad	303.61	304.03	0.4204
17	35	Biased-30krad	302.32	302.61	0.2862
18	35	Biased-30krad	304.26	304.6	0.3424
19	35	Biased-30krad	300.61	300.92	0.3049
20	35	Biased-30krad	300.8	301	0.2019
30	50	Unbiased-50krad	302.72	303.01	0.2924
31	50	Unbiased-50krad	299.42	299.68	0.2643
32	50	Unbiased-50krad	304.48	304.69	0.2112
33	50	Unbiased-50krad	302.99	303.18	0.1893
34	50	Unbiased-50krad	305.79	305.92	0.1394
40	55	Biased-50krad	300.75	300.89	0.1363
41	55	Biased-50krad	302.17	302.41	0.2362
42	55	Biased-50krad	305.13	305.4	0.2674
43	55	Biased-50krad	303.45	303.73	0.2799
44	55	Biased-50krad	301.54	301.65	0.1081
45	100	Unbiased-100krad	301.24	301.32	0.08
46	100	Unbiased-100krad	302.38	302.57	0.1925
47	100	Unbiased-100krad	301.25	301.25	0.0051
48	100	Unbiased-100krad	301.15	301.28	0.1238
49	100	Unbiased-100krad	304.56	304.69	0.13
50	105	Biased-100krad	303.94	304.32	0.3798
51	105	Biased-100krad	300.9	301.18	0.2861
52	105	Biased-100krad	303.15	303.57	0.4204
53	105	Biased-100krad	301.98	302.32	0.3424
54	105	Biased-100krad	304.36	304.71	0.3423

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	301.46	303	303.95	1.3503	301.92	303.46	304.43	1.3453	0.4236	0.45687	0.4797	0.029469
30	300.49	302.42	304.76	1.879	300.71	302.69	305.08	1.9237	0.2174	0.2749	0.3237	0.049087
35	300.61	302.32	304.26	1.6312	300.92	302.63	304.6	1.6901	0.2019	0.31116	0.4204	0.079858
50	299.42	303.08	305.79	2.3883	299.68	303.3	305.92	2.3452	0.1394	0.21932	0.2924	0.060659
55	300.75	302.61	305.13	1.7192	300.89	302.82	305.4	1.7833	0.1081	0.20558	0.2799	0.078398
100	301.15	302.12	304.56	1.4571	301.25	302.22	304.69	1.4884	0.0051	0.10628	0.1925	0.069339
105	300.9	302.87	304.36	1.426	301.18	303.22	304.71	1.4568	0.2861	0.3542	0.4204	0.049891

Device Test: 31.10 _PWRGD|RisingGood/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





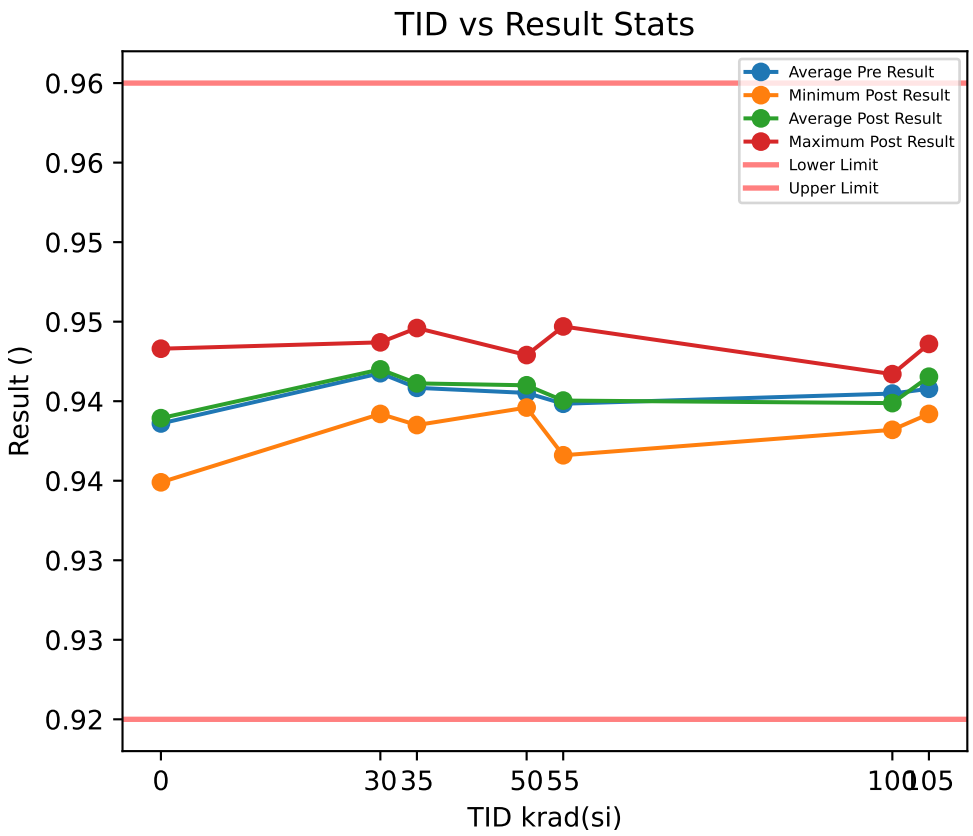
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

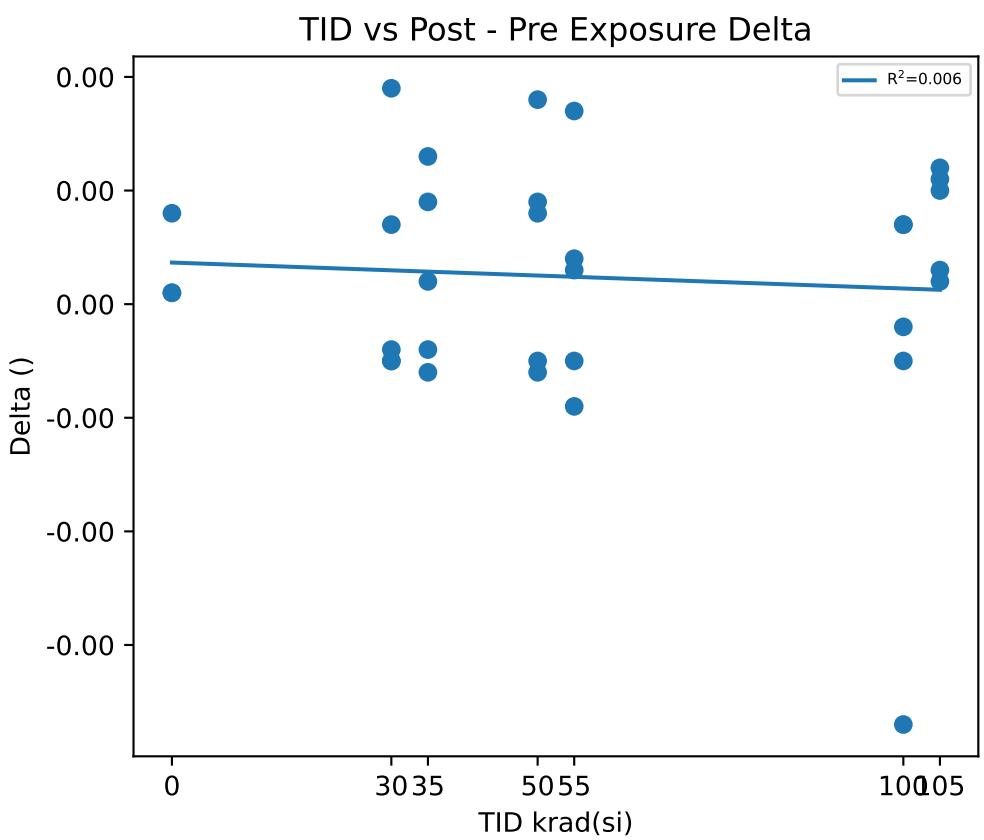
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9445	0.9446	0.0001
2	0	CU2	0.9405	0.9406	0.0001
3	0	CU3	0.9381	0.9381	0
11	30	Unbiased-30krad	0.9367	0.9363	-0.0004
12	30	Unbiased-30krad	0.9411	0.9414	0.0003
13	30	Unbiased-30krad	0.9415	0.9435	0.002
14	30	Unbiased-30krad	0.9385	0.9387	0.0002
15	30	Unbiased-30krad	0.9378	0.9394	0.0016
16	35	Biased-30krad	0.94	0.9409	0.0009
17	35	Biased-30krad	0.9394	0.9404	0.001
18	35	Biased-30krad	0.94	0.9412	0.0012
19	35	Biased-30krad	0.943	0.9443	0.0013
20	35	Biased-30krad	0.9416	0.9427	0.0011
30	50	Unbiased-50krad	0.9387	0.9395	0.0008
31	50	Unbiased-50krad	0.9398	0.9389	-0.0009
32	50	Unbiased-50krad	0.9391	0.94	0.0009
33	50	Unbiased-50krad	0.9389	0.9385	-0.0004
34	50	Unbiased-50krad	0.9397	0.9407	0.001
40	55	Biased-50krad	0.9431	0.9437	0.0006
41	55	Biased-50krad	0.9427	0.9432	0.0005
42	55	Biased-50krad	0.9366	0.9382	0.0016
43	55	Biased-50krad	0.9405	0.9408	0.0003
44	55	Biased-50krad	0.9408	0.9415	0.0007
45	100	Unbiased-100krad	0.9435	0.9429	-0.0006
46	100	Unbiased-100krad	0.9386	0.9401	0.0015
47	100	Unbiased-100krad	0.9407	0.9414	0.0007
48	100	Unbiased-100krad	0.9434	0.9423	-0.0011
49	100	Unbiased-100krad	0.9406	0.9411	0.0005
50	105	Biased-100krad	0.9394	0.9385	-0.0009
51	105	Biased-100krad	0.939	0.9418	0.0028
52	105	Biased-100krad	0.9386	0.9406	0.002
53	105	Biased-100krad	0.941	0.9394	-0.0016
54	105	Biased-100krad	0.9441	0.9446	0.0005

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9381	0.94103	0.9445	0.0032332	0.9381	0.9411	0.9446	0.0032787	0	6.6667e-05	0.0001	5.7735e-05
30	0.9367	0.93912	0.9415	0.0020957	0.9363	0.93986	0.9435	0.0027318	-0.0004	0.00074	0.002	0.0010139
35	0.9394	0.9408	0.943	0.0014765	0.9404	0.9419	0.9443	0.0015922	0.0009	0.0011	0.0013	0.00015811
50	0.9387	0.93924	0.9398	0.00048785	0.9385	0.93952	0.9407	0.00087293	-0.0009	0.00028	0.001	0.00087006
55	0.9366	0.94074	0.9431	0.0025793	0.9382	0.94148	0.9437	0.0021856	0.0003	0.00074	0.0016	0.00050299
100	0.9386	0.94136	0.9435	0.002084	0.9401	0.94156	0.9429	0.0010854	-0.0011	0.0002	0.0015	0.001044
105	0.9386	0.94042	0.9441	0.0022499	0.9385	0.94098	0.9446	0.0023753	-0.0016	0.00056	0.0028	0.0018636

Device Test: 31.11 _PWRGD|RisingGood/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





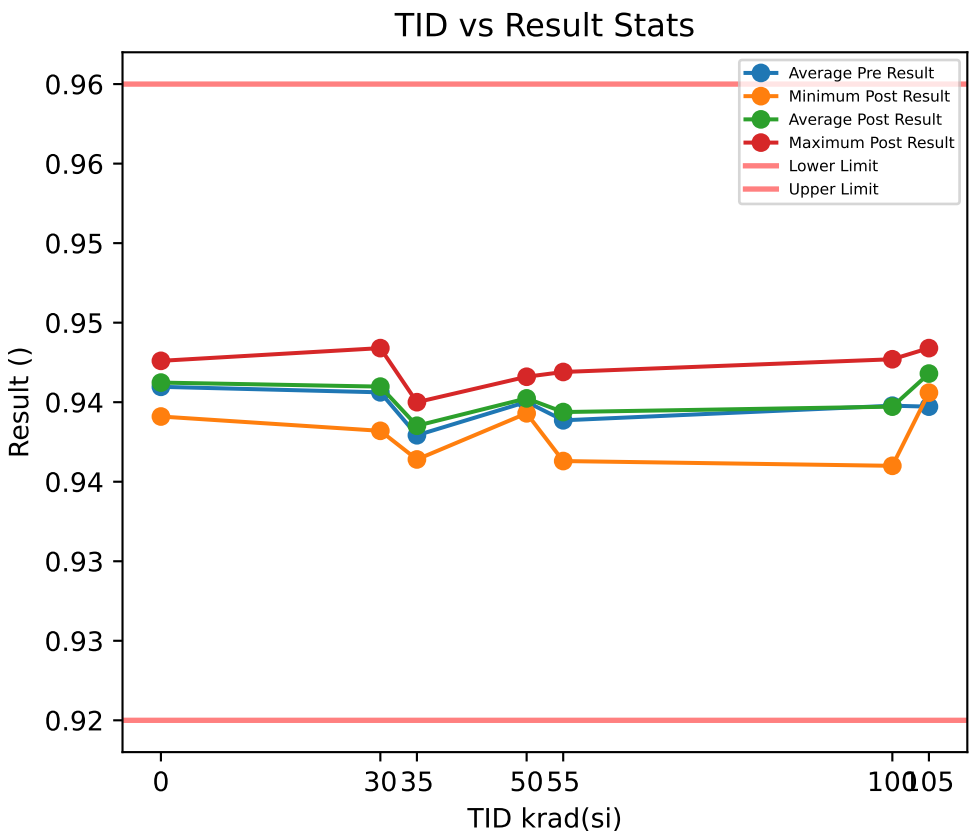
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

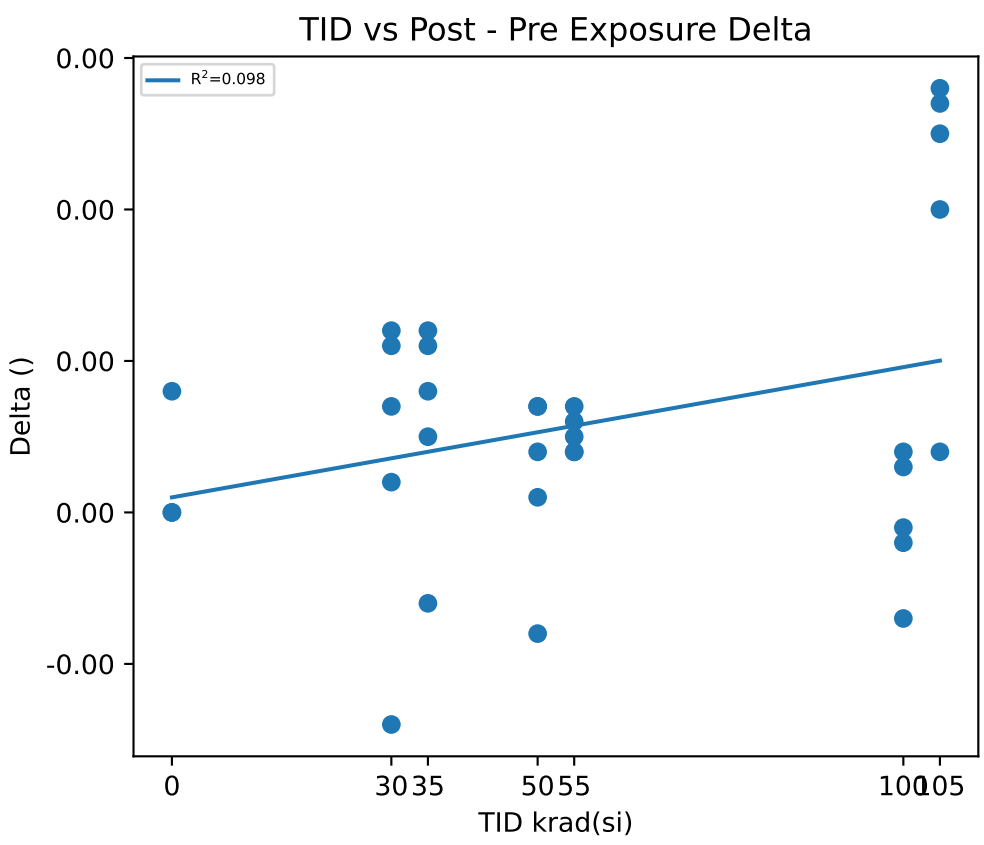
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9432	0.9433	0.0001
2	0	CU2	0.9348	0.9349	0.0001
3	0	CU3	0.9378	0.9386	0.0008
11	30	Unbiased-30krad	0.9441	0.9437	-0.0004
12	30	Unbiased-30krad	0.9417	0.9436	0.0019
13	30	Unbiased-30krad	0.9438	0.9433	-0.0005
14	30	Unbiased-30krad	0.9397	0.9392	-0.0005
15	30	Unbiased-30krad	0.9395	0.9402	0.0007
16	35	Biased-30krad	0.9408	0.9417	0.0009
17	35	Biased-30krad	0.9411	0.9405	-0.0006
18	35	Biased-30krad	0.9407	0.9403	-0.0004
19	35	Biased-30krad	0.9433	0.9446	0.0013
20	35	Biased-30krad	0.9383	0.9385	0.0002
30	50	Unbiased-50krad	0.9387	0.9396	0.0009
31	50	Unbiased-50krad	0.9388	0.9396	0.0008
32	50	Unbiased-50krad	0.9407	0.9425	0.0018
33	50	Unbiased-50krad	0.9409	0.9404	-0.0005
34	50	Unbiased-50krad	0.9435	0.9429	-0.0006
40	55	Biased-50krad	0.9411	0.9406	-0.0005
41	55	Biased-50krad	0.9393	0.9396	0.0003
42	55	Biased-50krad	0.943	0.9447	0.0017
43	55	Biased-50krad	0.9383	0.9387	0.0004
44	55	Biased-50krad	0.9375	0.9366	-0.0009
45	100	Unbiased-100krad	0.9378	0.9385	0.0007
46	100	Unbiased-100krad	0.9403	0.9401	-0.0002
47	100	Unbiased-100krad	0.9387	0.9382	-0.0005
48	100	Unbiased-100krad	0.941	0.9417	0.0007
49	100	Unbiased-100krad	0.9446	0.9409	-0.0037
50	105	Biased-100krad	0.9399	0.9409	0.001
51	105	Biased-100krad	0.9433	0.9436	0.0003
52	105	Biased-100krad	0.9404	0.9415	0.0011
53	105	Biased-100krad	0.939	0.9392	0.0002
54	105	Biased-100krad	0.9413	0.9425	0.0012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9348	0.9386	0.9432	0.0042568	0.9349	0.93893	0.9433	0.0042099	0.0001	0.00033333	0.0008	0.00040415
30	0.9395	0.94176	0.9441	0.002179	0.9392	0.942	0.9437	0.0021342	-0.0005	0.00024	0.0019	0.0010574
35	0.9383	0.94084	0.9433	0.0017743	0.9385	0.94112	0.9446	0.0022565	-0.0006	0.00028	0.0013	0.0008167
50	0.9387	0.94052	0.9435	0.0019575	0.9396	0.941	0.9429	0.0015922	-0.0006	0.00048	0.0018	0.0010183
55	0.9375	0.93984	0.943	0.0022199	0.9366	0.94004	0.9447	0.0029938	-0.0009	0.0002	0.0017	0.001
100	0.9378	0.94048	0.9446	0.0026281	0.9382	0.93988	0.9417	0.0015106	-0.0037	-0.0006	0.0007	0.0018138
105	0.939	0.94078	0.9433	0.0016362	0.9392	0.94154	0.9436	0.0016622	0.0002	0.00076	0.0012	0.00047223

Device Test: 31.12 _PWRGD|RisingGood/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





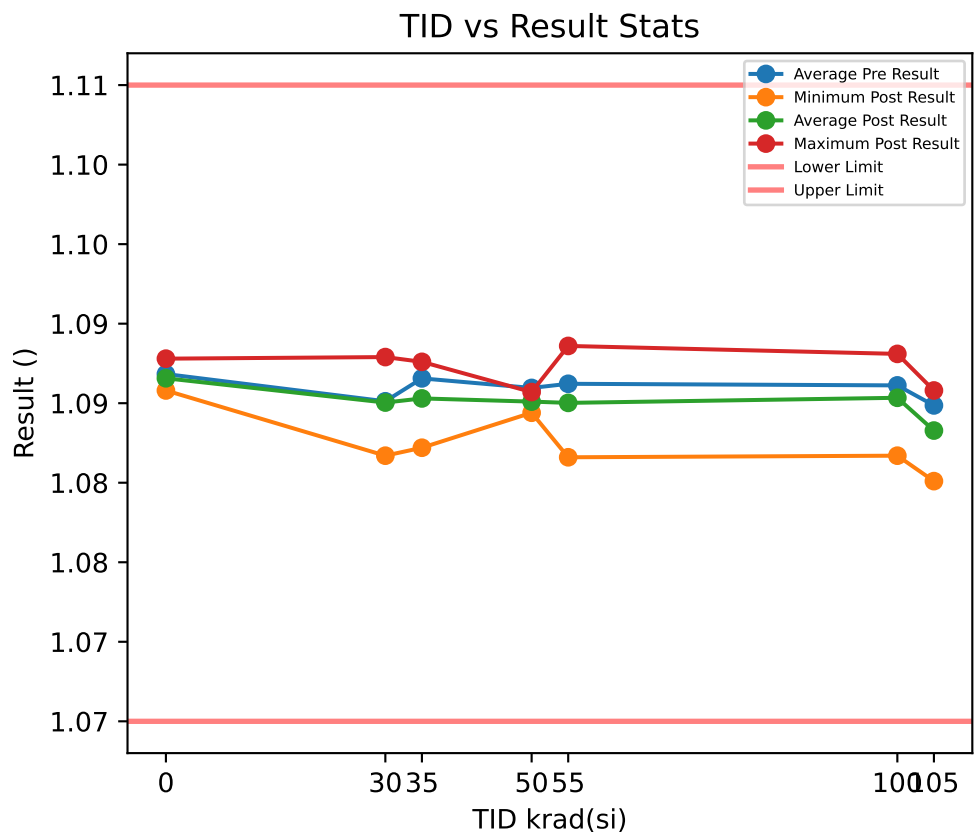
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

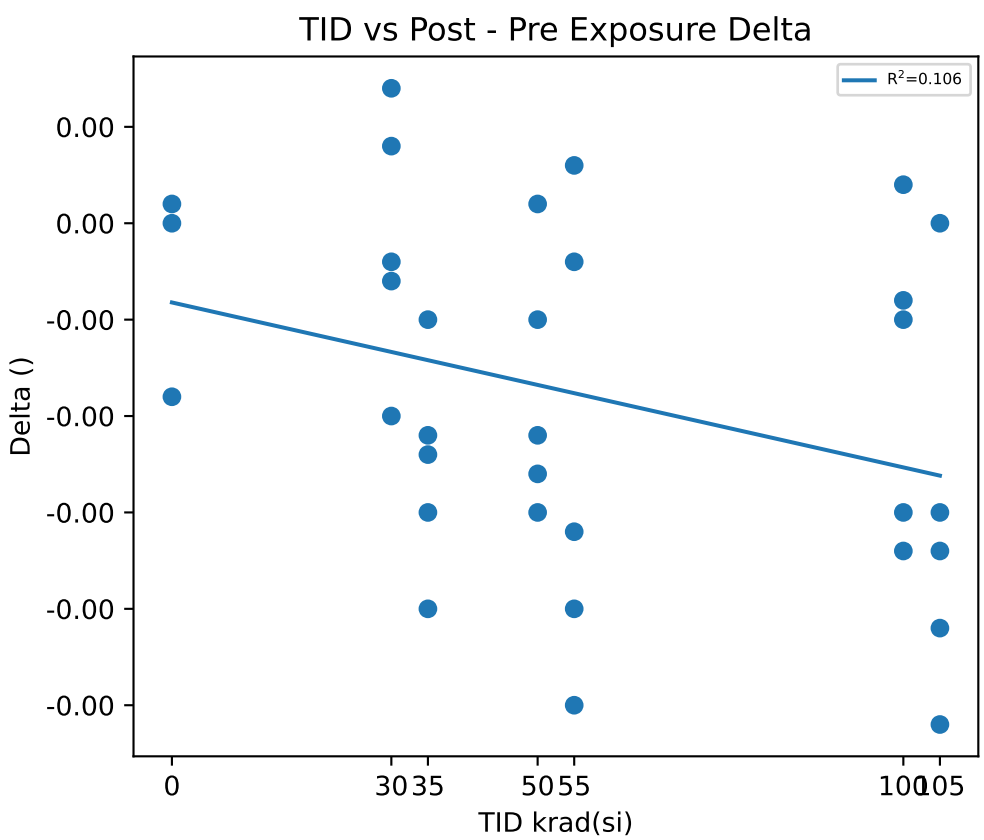
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9426	0.9426	0
2	0	CU2	0.9391	0.9391	0
3	0	CU3	0.9412	0.942	0.0008
11	30	Unbiased-30krad	0.9421	0.9407	-0.0014
12	30	Unbiased-30krad	0.938	0.9382	0.0002
13	30	Unbiased-30krad	0.9391	0.9403	0.0012
14	30	Unbiased-30krad	0.9423	0.9434	0.0011
15	30	Unbiased-30krad	0.9416	0.9423	0.0007
16	35	Biased-30krad	0.9356	0.9364	0.0008
17	35	Biased-30krad	0.9391	0.9385	-0.0006
18	35	Biased-30krad	0.938	0.9392	0.0012
19	35	Biased-30krad	0.9395	0.94	0.0005
20	35	Biased-30krad	0.9374	0.9385	0.0011
30	50	Unbiased-50krad	0.94	0.9407	0.0007
31	50	Unbiased-50krad	0.9386	0.9393	0.0007
32	50	Unbiased-50krad	0.9407	0.9399	-0.0008
33	50	Unbiased-50krad	0.9393	0.9397	0.0004
34	50	Unbiased-50krad	0.9415	0.9416	0.0001
40	55	Biased-50krad	0.9412	0.9416	0.0004
41	55	Biased-50krad	0.9415	0.9419	0.0004
42	55	Biased-50krad	0.9388	0.9394	0.0006
43	55	Biased-50krad	0.9372	0.9377	0.0005
44	55	Biased-50krad	0.9356	0.9363	0.0007
45	100	Unbiased-100krad	0.9434	0.9427	-0.0007
46	100	Unbiased-100krad	0.9412	0.941	-0.0002
47	100	Unbiased-100krad	0.9394	0.9398	0.0004
48	100	Unbiased-100krad	0.9361	0.936	-0.0001
49	100	Unbiased-100krad	0.9388	0.9391	0.0003
50	105	Biased-100krad	0.9391	0.9416	0.0025
51	105	Biased-100krad	0.9402	0.9406	0.0004
52	105	Biased-100krad	0.9399	0.9419	0.002
53	105	Biased-100krad	0.9407	0.9434	0.0027
54	105	Biased-100krad	0.9387	0.9415	0.0028

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9391	0.94097	0.9426	0.0017616	0.9391	0.94123	0.9426	0.0018717	0	0.00026667	0.0008	0.00046188
30	0.938	0.94062	0.9423	0.001946	0.9382	0.94098	0.9434	0.0019917	-0.0014	0.00036	0.0012	0.0010597
35	0.9356	0.93792	0.9395	0.001545	0.9364	0.93852	0.94	0.0013368	-0.0006	0.0006	0.0012	0.00072457
50	0.9386	0.94002	0.9415	0.0011389	0.9393	0.94024	0.9416	0.00091542	-0.0008	0.00022	0.0007	0.00062209
55	0.9356	0.93886	0.9415	0.0025413	0.9363	0.93938	0.9419	0.0024284	0.0004	0.00052	0.0007	0.00013038
100	0.9361	0.93978	0.9434	0.002728	0.936	0.93972	0.9427	0.0024874	-0.0007	-6e-05	0.0004	0.00043932
105	0.9387	0.93972	0.9407	0.00081363	0.9406	0.9418	0.9434	0.0010173	0.0004	0.00208	0.0028	0.00098843

Device Test: 31.13 _PWRGD|RisingFault/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





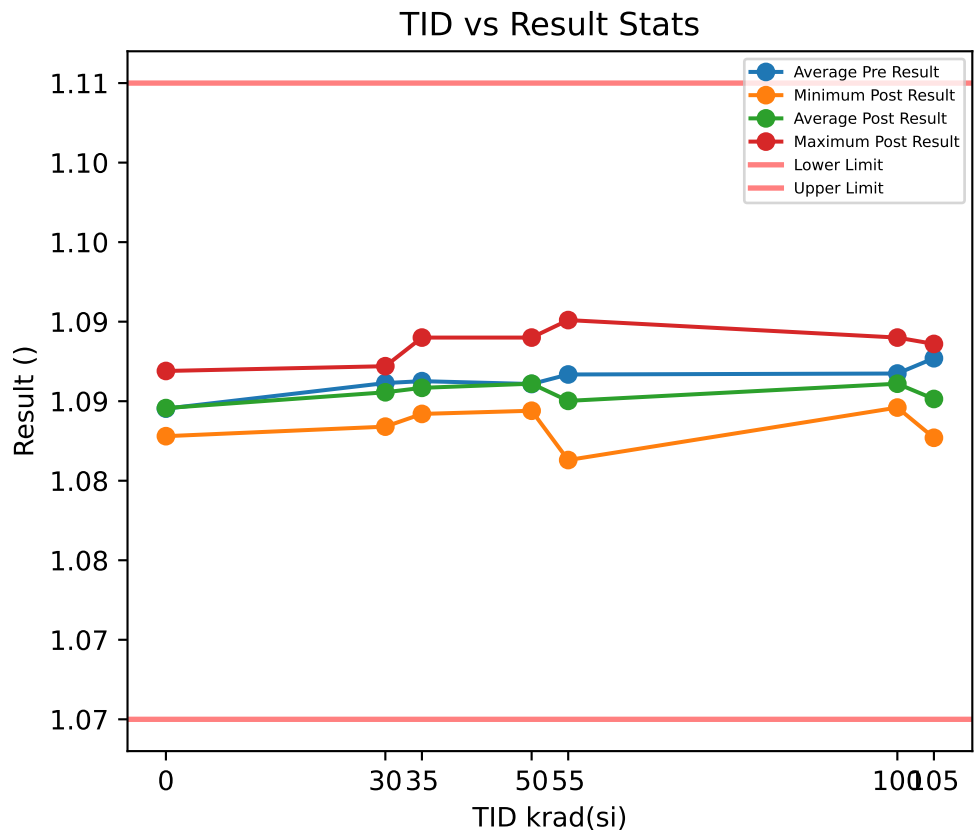
Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

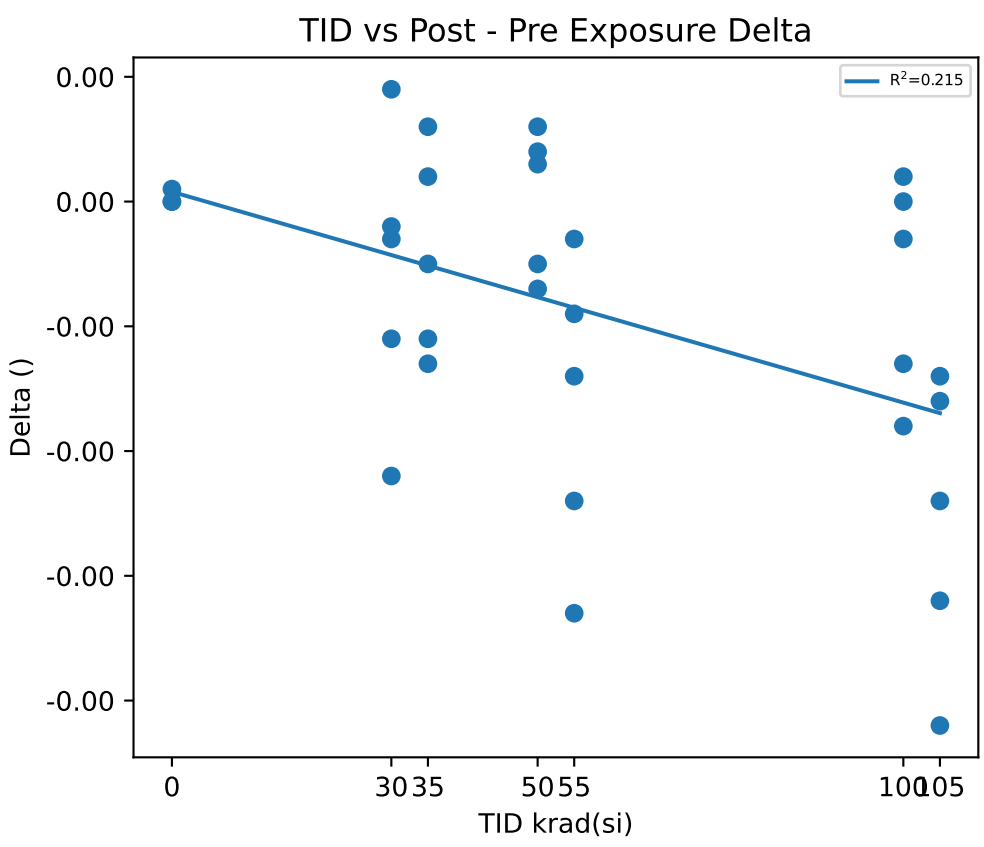
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0907	1.0908	0.0001
2	0	CU2	1.0911	1.0911	0
3	0	CU3	1.0937	1.0928	-0.0009
11	30	Unbiased-30krad	1.0909	1.0916	0.0007
12	30	Unbiased-30krad	1.0863	1.0867	0.0004
13	30	Unbiased-30krad	1.0886	1.0883	-0.0003
14	30	Unbiased-30krad	1.0931	1.0929	-0.0002
15	30	Unbiased-30krad	1.0917	1.0907	-0.001
16	35	Biased-30krad	1.0887	1.0872	-0.0015
17	35	Biased-30krad	1.0909	1.0897	-0.0012
18	35	Biased-30krad	1.0937	1.0926	-0.0011
19	35	Biased-30krad	1.092	1.09	-0.002
20	35	Biased-30krad	1.0925	1.092	-0.0005
30	50	Unbiased-50krad	1.0893	1.0894	0.0001
31	50	Unbiased-50krad	1.0903	1.0898	-0.0005
32	50	Unbiased-50krad	1.0918	1.0903	-0.0015
33	50	Unbiased-50krad	1.0914	1.0903	-0.0011
34	50	Unbiased-50krad	1.092	1.0907	-0.0013
40	55	Biased-50krad	1.0902	1.0886	-0.0016
41	55	Biased-50krad	1.0956	1.0936	-0.002
42	55	Biased-50krad	1.0907	1.091	0.0003
43	55	Biased-50krad	1.0905	1.0903	-0.0002
44	55	Biased-50krad	1.0891	1.0866	-0.0025
45	100	Unbiased-100krad	1.0943	1.0926	-0.0017
46	100	Unbiased-100krad	1.0899	1.0884	-0.0015
47	100	Unbiased-100krad	1.0871	1.0867	-0.0004
48	100	Unbiased-100krad	1.0936	1.0931	-0.0005
49	100	Unbiased-100krad	1.0907	1.0909	0.0002
50	105	Biased-100krad	1.0897	1.0876	-0.0021
51	105	Biased-100krad	1.0934	1.0908	-0.0026
52	105	Biased-100krad	1.0866	1.0851	-0.0015
53	105	Biased-100krad	1.0903	1.0903	0
54	105	Biased-100krad	1.0893	1.0876	-0.0017

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0907	1.0918	1.0937	0.0016289	1.0908	1.0916	1.0928	0.0010786	-0.0009	-0.00026667	0.0001	0.00055076
30	1.0863	1.0901	1.0931	0.0026874	1.0867	1.09	1.0929	0.0025116	-0.001	-8e-05	0.0007	0.00066106
35	1.0887	1.0916	1.0937	0.0018889	1.0872	1.0903	1.0926	0.0021354	-0.002	-0.00126	-0.0005	0.00055045
50	1.0893	1.091	1.092	0.0011371	1.0894	1.0901	1.0907	0.00050498	-0.0015	-0.00086	0.0001	0.00065422
55	1.0891	1.0912	1.0956	0.0025253	1.0866	1.09	1.0936	0.0026253	-0.0025	-0.0012	0.0003	0.0011979
100	1.0871	1.0911	1.0943	0.0029192	1.0867	1.0903	1.0931	0.002741	-0.0017	-0.00078	0.0002	0.00079812
105	1.0866	1.0899	1.0934	0.0024337	1.0851	1.0883	1.0908	0.0023167	-0.0026	-0.00158	0	0.00097826

Device Test: 31.14 _PWRGD|RisingFault/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





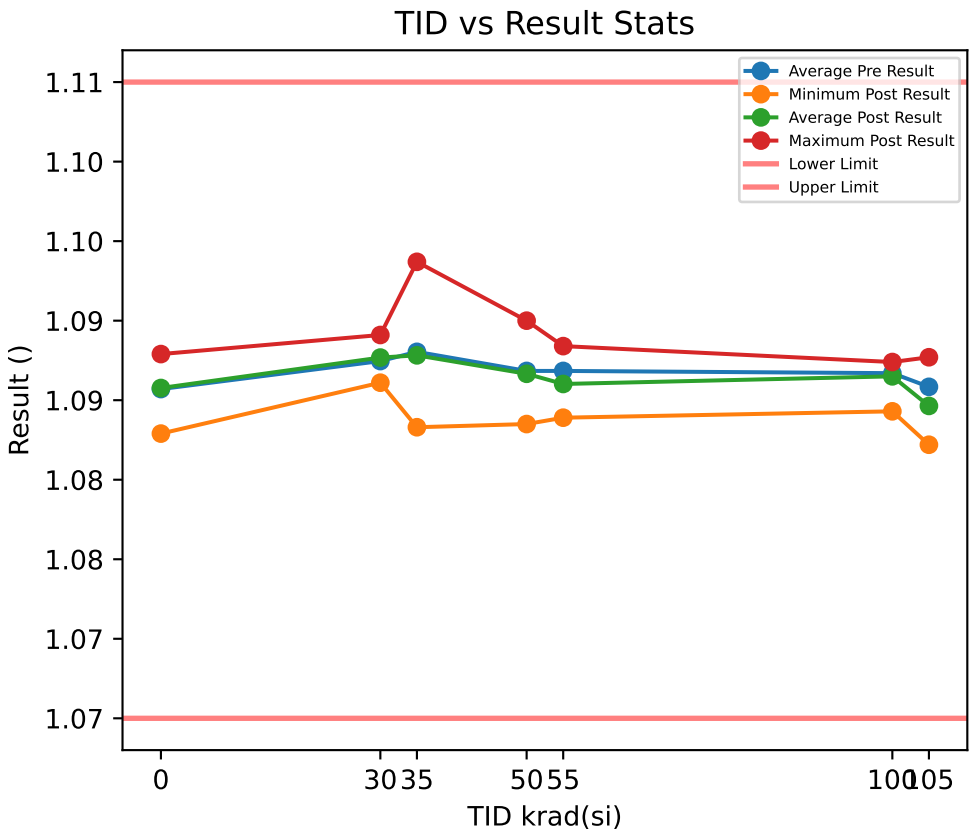
Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

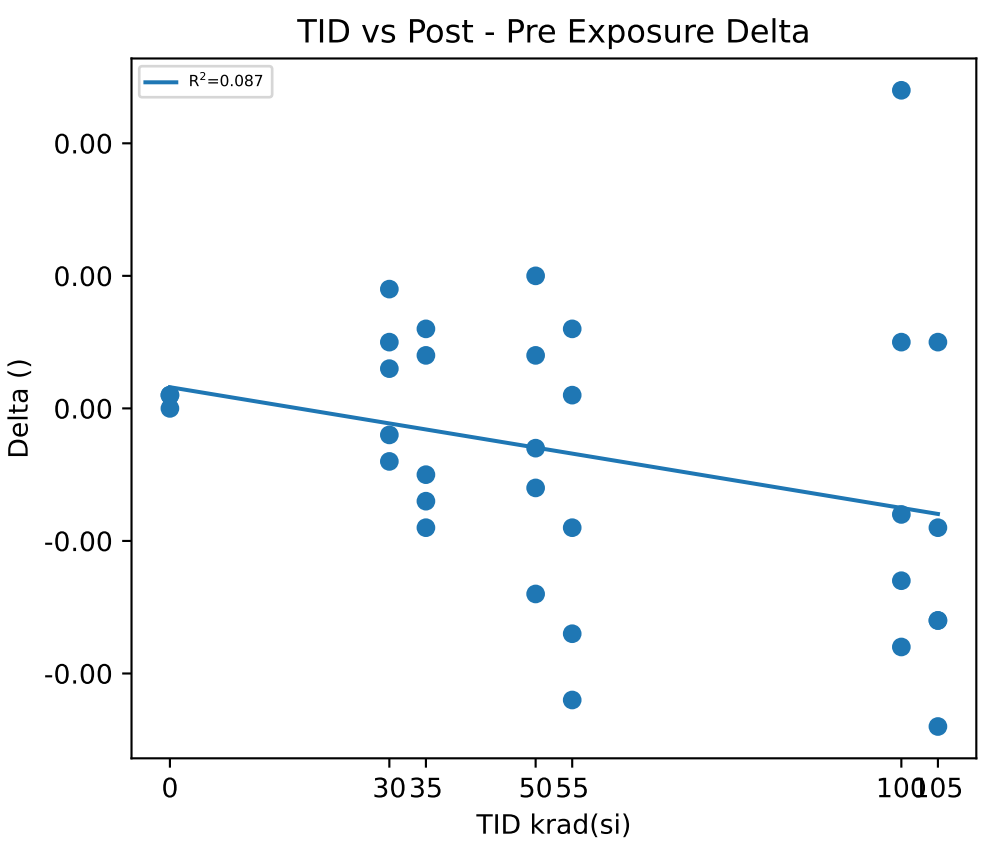
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0919	1.0919	0
2	0	CU2	1.0877	1.0878	0.0001
3	0	CU3	1.089	1.089	0
11	30	Unbiased-30krad	1.091	1.0908	-0.0002
12	30	Unbiased-30krad	1.0929	1.0907	-0.0022
13	30	Unbiased-30krad	1.0918	1.0907	-0.0011
14	30	Unbiased-30krad	1.0887	1.0884	-0.0003
15	30	Unbiased-30krad	1.0913	1.0922	0.0009
16	35	Biased-30krad	1.0912	1.0914	0.0002
17	35	Biased-30krad	1.0897	1.0892	-0.0005
18	35	Biased-30krad	1.0892	1.0898	0.0006
19	35	Biased-30krad	1.0909	1.0898	-0.0011
20	35	Biased-30krad	1.0953	1.094	-0.0013
30	50	Unbiased-50krad	1.0905	1.0898	-0.0007
31	50	Unbiased-50krad	1.0899	1.0894	-0.0005
32	50	Unbiased-50krad	1.09	1.0903	0.0003
33	50	Unbiased-50krad	1.0934	1.094	0.0006
34	50	Unbiased-50krad	1.0916	1.092	0.0004
40	55	Biased-50krad	1.093	1.0897	-0.0033
41	55	Biased-50krad	1.0872	1.0863	-0.0009
42	55	Biased-50krad	1.0916	1.0902	-0.0014
43	55	Biased-50krad	1.0954	1.0951	-0.0003
44	55	Biased-50krad	1.0912	1.0888	-0.0024
45	100	Unbiased-100krad	1.0931	1.0913	-0.0018
46	100	Unbiased-100krad	1.094	1.094	0
47	100	Unbiased-100krad	1.0911	1.0908	-0.0003
48	100	Unbiased-100krad	1.0911	1.0898	-0.0013
49	100	Unbiased-100krad	1.0894	1.0896	0.0002
50	105	Biased-100krad	1.095	1.0936	-0.0014
51	105	Biased-100krad	1.0909	1.0877	-0.0032
52	105	Biased-100krad	1.091	1.0894	-0.0016
53	105	Biased-100krad	1.0936	1.0894	-0.0042
54	105	Biased-100krad	1.093	1.0906	-0.0024

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0877	1.0895	1.0919	0.0021502	1.0878	1.0896	1.0919	0.0021079	0	3.3333e-05	0.0001	5.7735e-05
30	1.0887	1.0911	1.0929	0.0015437	1.0884	1.0906	1.0922	0.0013649	-0.0022	-0.00058	0.0009	0.001152
35	1.0892	1.0913	1.0953	0.0024048	1.0892	1.0908	1.094	0.0019463	-0.0013	-0.00042	0.0006	0.0008167
50	1.0899	1.0911	1.0934	0.0014618	1.0894	1.0911	1.094	0.0019	-0.0007	2e-05	0.0006	0.00058052
55	1.0872	1.0917	1.0954	0.0029953	1.0863	1.09	1.0951	0.003212	-0.0033	-0.00166	-0.0003	0.0011971
100	1.0894	1.0917	1.094	0.0018202	1.0896	1.0911	1.094	0.0017664	-0.0018	-0.00064	0.0002	0.00086776
105	1.0909	1.0927	1.095	0.001755	1.0877	1.0901	1.0936	0.0021927	-0.0042	-0.00256	-0.0014	0.001161

Device Test: 31.15 _PWRGD|RisingFault/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





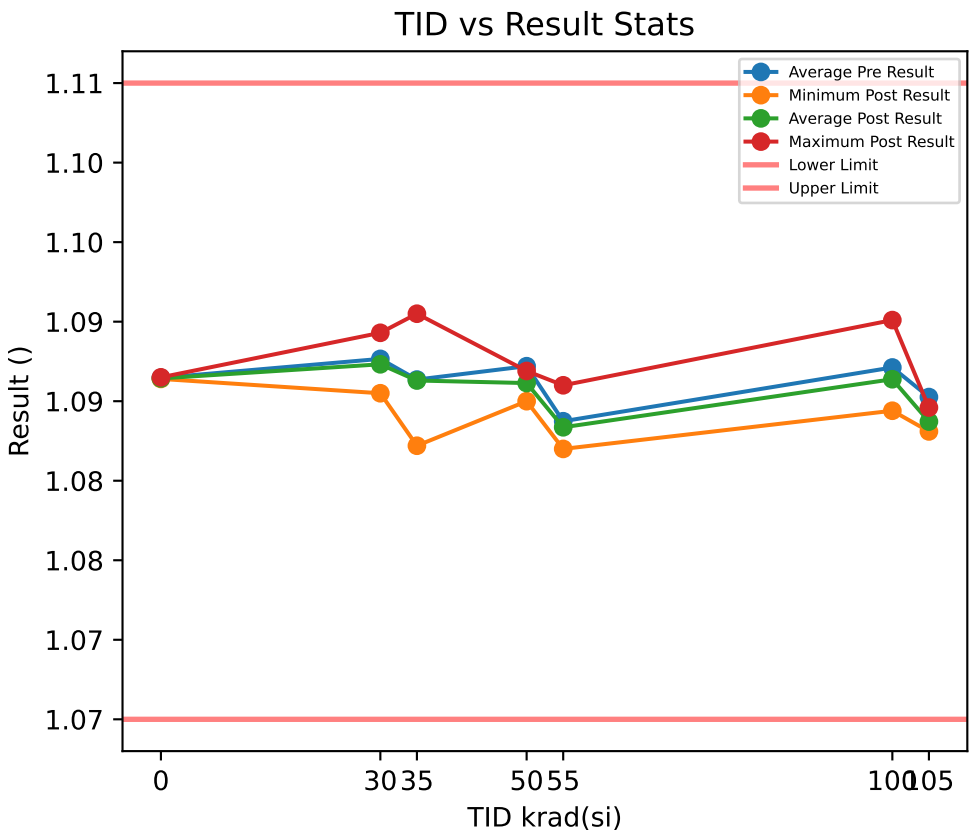
Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

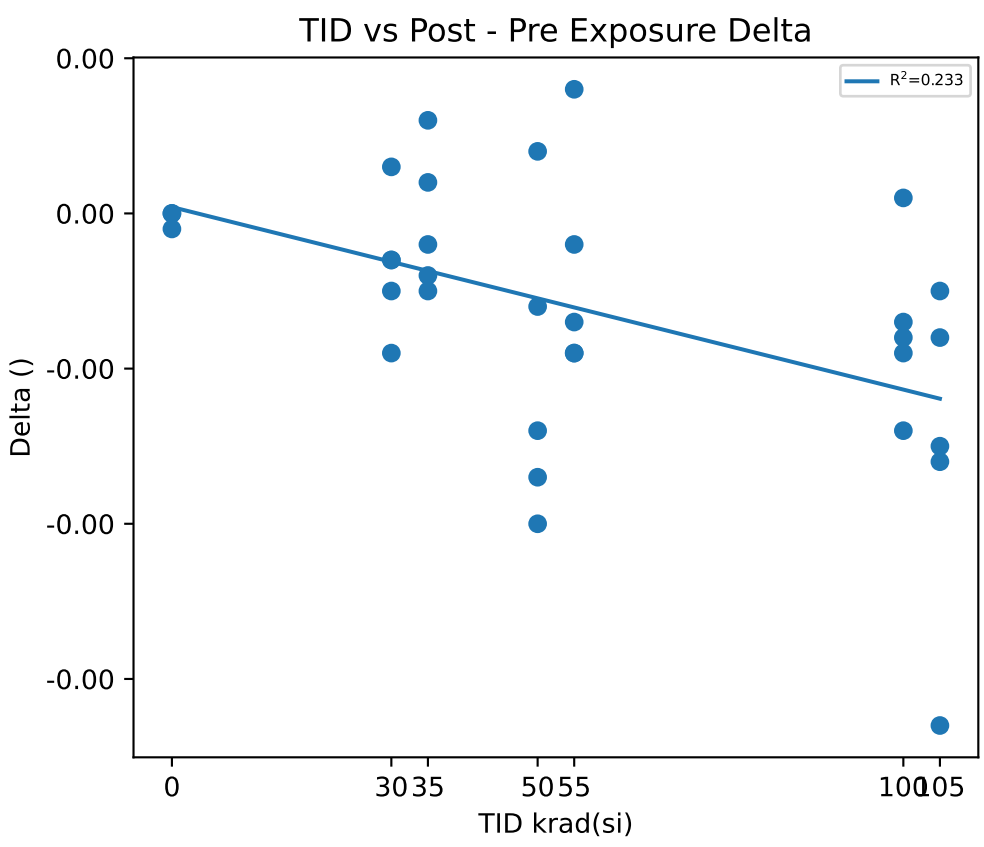
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0928	1.0929	0.0001
2	0	CU2	1.0914	1.0915	0.0001
3	0	CU3	1.0879	1.0879	0
11	30	Unbiased-30krad	1.0941	1.0939	-0.0002
12	30	Unbiased-30krad	1.0938	1.0941	0.0003
13	30	Unbiased-30krad	1.0924	1.0929	0.0005
14	30	Unbiased-30krad	1.0915	1.0911	-0.0004
15	30	Unbiased-30krad	1.0905	1.0914	0.0009
16	35	Biased-30krad	1.0912	1.0905	-0.0007
17	35	Biased-30krad	1.0967	1.0962	-0.0005
18	35	Biased-30krad	1.0877	1.0883	0.0006
19	35	Biased-30krad	1.0996	1.0987	-0.0009
20	35	Biased-30krad	1.09	1.0904	0.0004
30	50	Unbiased-50krad	1.094	1.095	0.001
31	50	Unbiased-50krad	1.0934	1.092	-0.0014
32	50	Unbiased-50krad	1.0926	1.092	-0.0006
33	50	Unbiased-50krad	1.0911	1.0908	-0.0003
34	50	Unbiased-50krad	1.0881	1.0885	0.0004
40	55	Biased-50krad	1.0951	1.0934	-0.0017
41	55	Biased-50krad	1.0902	1.0908	0.0006
42	55	Biased-50krad	1.0911	1.0889	-0.0022
43	55	Biased-50krad	1.091	1.0901	-0.0009
44	55	Biased-50krad	1.0918	1.0919	0.0001
45	100	Unbiased-100krad	1.0888	1.0912	0.0024
46	100	Unbiased-100krad	1.0932	1.0924	-0.0008
47	100	Unbiased-100krad	1.0906	1.0893	-0.0013
48	100	Unbiased-100krad	1.0919	1.0924	0.0005
49	100	Unbiased-100krad	1.094	1.0922	-0.0018
50	105	Biased-100krad	1.0876	1.0881	0.0005
51	105	Biased-100krad	1.0919	1.0903	-0.0016
52	105	Biased-100krad	1.0943	1.0927	-0.0016
53	105	Biased-100krad	1.0896	1.0872	-0.0024
54	105	Biased-100krad	1.0908	1.0899	-0.0009

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0879	1.0907	1.0928	0.0025239	1.0879	1.0908	1.0929	0.0025794	0	6.6667e-05	0.0001	5.7735e-05
30	1.0905	1.0925	1.0941	0.0015209	1.0911	1.0927	1.0941	0.0013864	-0.0004	0.00022	0.0009	0.00052631
35	1.0877	1.093	1.0996	0.0049389	1.0883	1.0928	1.0987	0.0044065	-0.0009	-0.00022	0.0006	0.00067602
50	1.0881	1.0918	1.094	0.0023565	1.0885	1.0917	1.095	0.0023512	-0.0014	-0.00018	0.001	0.00092304
55	1.0902	1.0918	1.0951	0.0019087	1.0889	1.091	1.0934	0.0017196	-0.0022	-0.00082	0.0006	0.0011777
100	1.0888	1.0917	1.094	0.0020736	1.0893	1.0915	1.0924	0.0013266	-0.0018	-0.0002	0.0024	0.0016867
105	1.0876	1.0908	1.0943	0.0025066	1.0872	1.0896	1.0927	0.0021326	-0.0024	-0.0012	0.0005	0.0010886

Device Test: 31.16 _PWRGD|RisingFault/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_FAULT





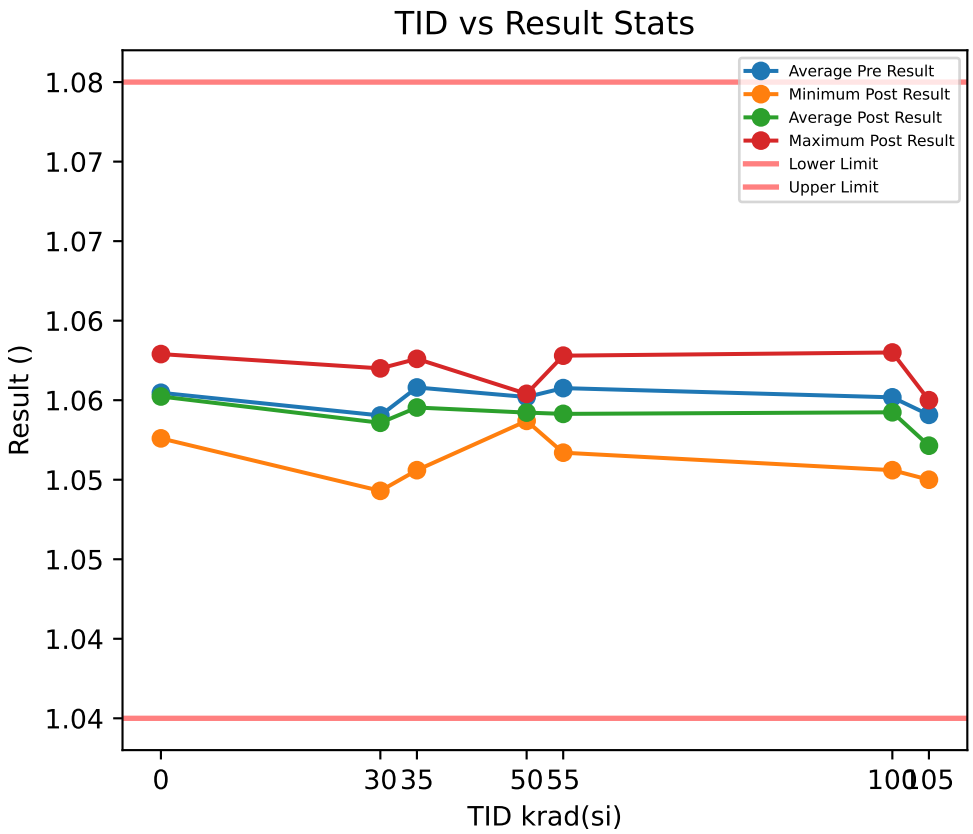
Test Results (Lower Limit = 1.07, Upper Limit = 1.11 ())

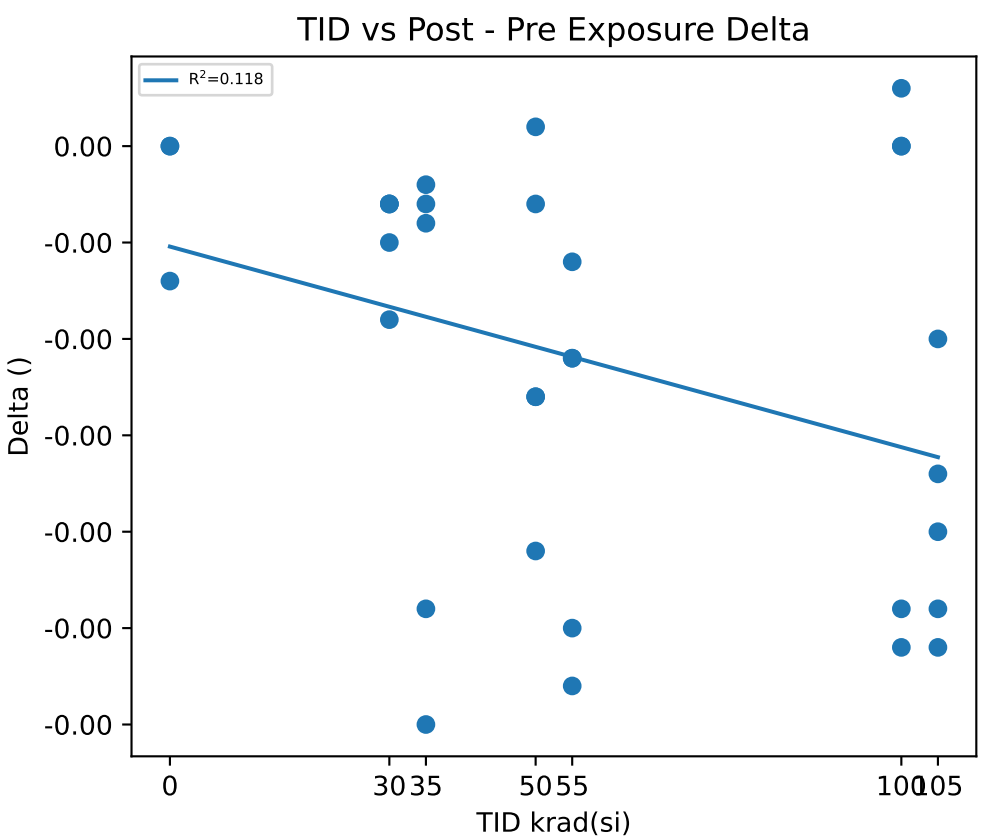
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0914	1.0914	0
2	0	CU2	1.0914	1.0914	0
3	0	CU3	1.0916	1.0915	-0.0001
11	30	Unbiased-30krad	1.0908	1.0905	-0.0003
12	30	Unbiased-30krad	1.0932	1.0935	0.0003
13	30	Unbiased-30krad	1.0918	1.0913	-0.0005
14	30	Unbiased-30krad	1.0946	1.0943	-0.0003
15	30	Unbiased-30krad	1.0929	1.092	-0.0009
16	35	Biased-30krad	1.091	1.0912	0.0002
17	35	Biased-30krad	1.091	1.0905	-0.0005
18	35	Biased-30krad	1.0949	1.0955	0.0006
19	35	Biased-30krad	1.0923	1.0921	-0.0002
20	35	Biased-30krad	1.0876	1.0872	-0.0004
30	50	Unbiased-50krad	1.0929	1.0912	-0.0017
31	50	Unbiased-50krad	1.0914	1.09	-0.0014
32	50	Unbiased-50krad	1.0919	1.0913	-0.0006
33	50	Unbiased-50krad	1.0939	1.0919	-0.002
34	50	Unbiased-50krad	1.0909	1.0913	0.0004
40	55	Biased-50krad	1.0919	1.091	-0.0009
41	55	Biased-50krad	1.0883	1.0874	-0.0009
42	55	Biased-50krad	1.0879	1.0872	-0.0007
43	55	Biased-50krad	1.0872	1.087	-0.0002
44	55	Biased-50krad	1.0884	1.0892	0.0008
45	100	Unbiased-100krad	1.0903	1.0894	-0.0009
46	100	Unbiased-100krad	1.0907	1.0908	0.0001
47	100	Unbiased-100krad	1.0958	1.0951	-0.0007
48	100	Unbiased-100krad	1.0914	1.09	-0.0014
49	100	Unbiased-100krad	1.0924	1.0916	-0.0008
50	105	Biased-100krad	1.0886	1.0881	-0.0005
51	105	Biased-100krad	1.0903	1.0888	-0.0015
52	105	Biased-100krad	1.0923	1.089	-0.0033
53	105	Biased-100krad	1.0904	1.0896	-0.0008
54	105	Biased-100krad	1.0897	1.0881	-0.0016

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0914	1.0915	1.0916	0.00011547	1.0914	1.0914	1.0915	5.7735e-05	-0.0001	-3.3333e-05	0	5.7735e-05
30	1.0908	1.0927	1.0946	0.0014415	1.0905	1.0923	1.0943	0.0015627	-0.0009	-0.00034	0.0003	0.00043359
35	1.0876	1.0914	1.0949	0.0026369	1.0872	1.0913	1.0955	0.0029891	-0.0005	-6e-05	0.0006	0.00045607
50	1.0909	1.0922	1.0939	0.0012042	1.09	1.0911	1.0919	0.00069498	-0.002	-0.00106	0.0004	0.0009685
55	1.0872	1.0887	1.0919	0.0018284	1.087	1.0884	1.091	0.001717	-0.0009	-0.00038	0.0008	0.00071903
100	1.0903	1.0921	1.0958	0.0022061	1.0894	1.0914	1.0951	0.0022387	-0.0014	-0.00074	0.0001	0.00054129
105	1.0886	1.0903	1.0923	0.0013465	1.0881	1.0887	1.0896	0.00063797	-0.0033	-0.00154	-0.0005	0.0010877

Device Test: 31.17 _PWRGD|FallingGood/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD





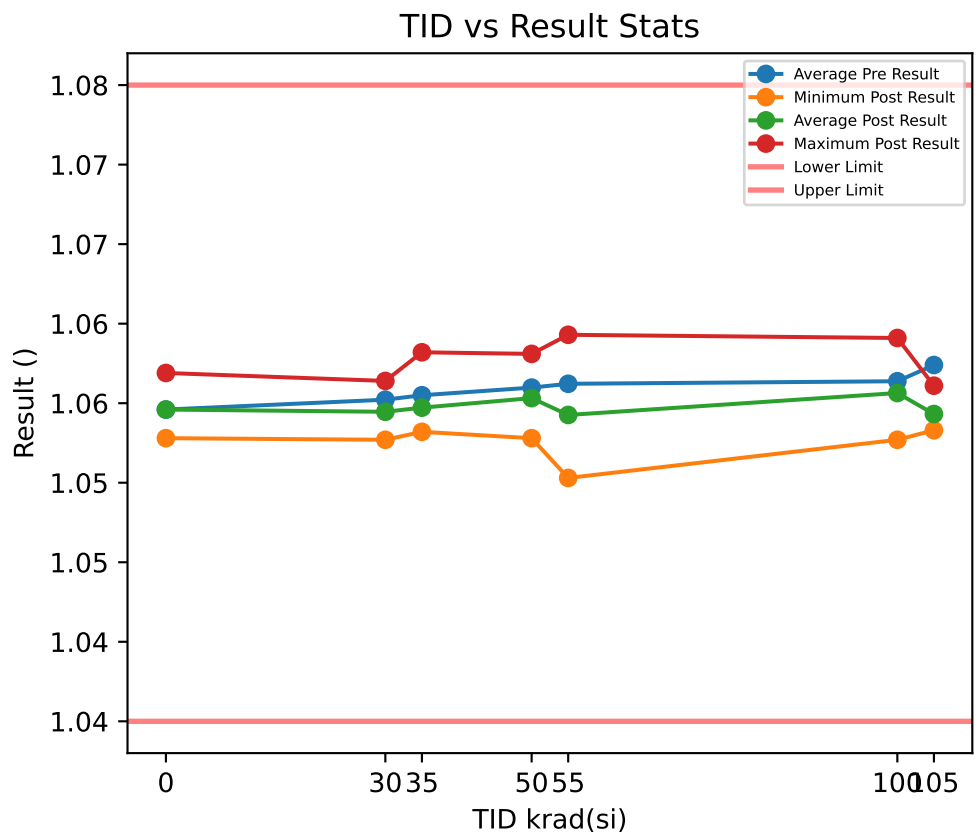
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

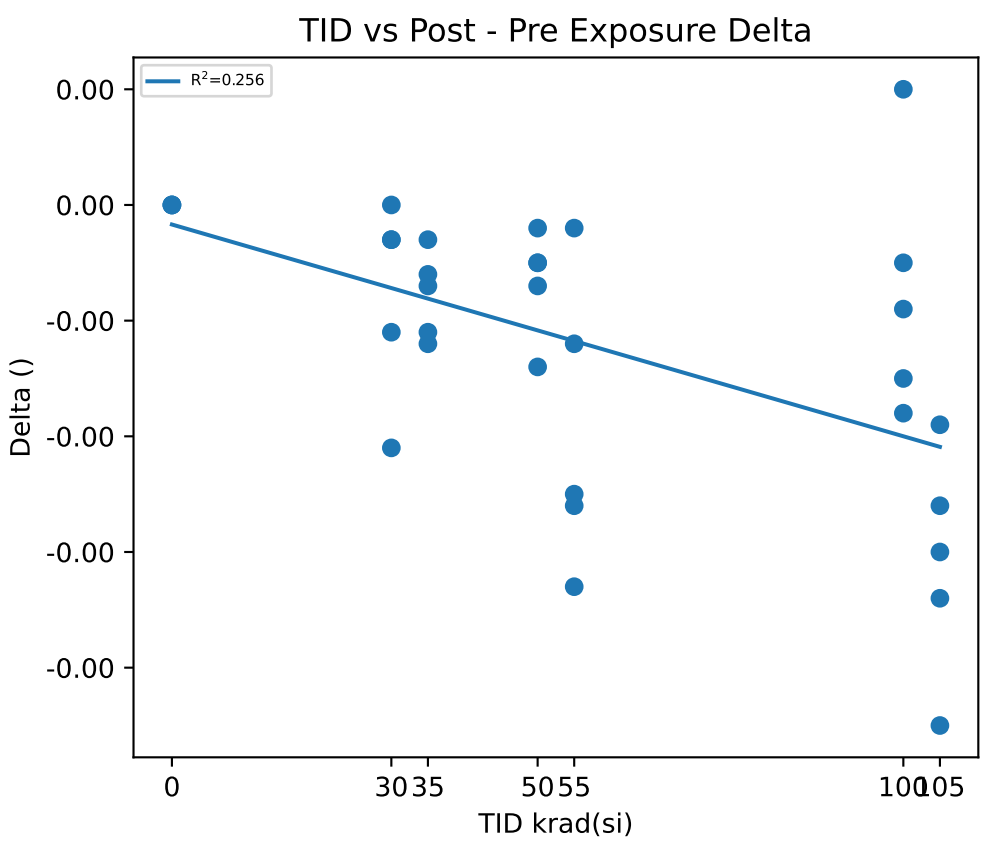
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0583	1.0576	-0.0007
2	0	CU2	1.0602	1.0602	0
3	0	CU3	1.0629	1.0629	0
11	30	Unbiased-30krad	1.0601	1.0598	-0.0003
12	30	Unbiased-30krad	1.0548	1.0543	-0.0005
13	30	Unbiased-30krad	1.0579	1.0576	-0.0003
14	30	Unbiased-30krad	1.0623	1.062	-0.0003
15	30	Unbiased-30krad	1.0601	1.0592	-0.0009
16	35	Biased-30krad	1.058	1.0556	-0.0024
17	35	Biased-30krad	1.0611	1.0581	-0.003
18	35	Biased-30krad	1.0628	1.0626	-0.0002
19	35	Biased-30krad	1.0604	1.0601	-0.0003
20	35	Biased-30krad	1.0617	1.0613	-0.0004
30	50	Unbiased-50krad	1.0586	1.0587	0.0001
31	50	Unbiased-50krad	1.0604	1.0591	-0.0013
32	50	Unbiased-50krad	1.0609	1.0588	-0.0021
33	50	Unbiased-50krad	1.0607	1.0604	-0.0003
34	50	Unbiased-50krad	1.0604	1.0591	-0.0013
40	55	Biased-50krad	1.0595	1.0567	-0.0028
41	55	Biased-50krad	1.0639	1.0628	-0.0011
42	55	Biased-50krad	1.0607	1.0601	-0.0006
43	55	Biased-50krad	1.0605	1.0594	-0.0011
44	55	Biased-50krad	1.0592	1.0567	-0.0025
45	100	Unbiased-100krad	1.0626	1.06	-0.0026
46	100	Unbiased-100krad	1.06	1.0576	-0.0024
47	100	Unbiased-100krad	1.0556	1.0556	0
48	100	Unbiased-100krad	1.0627	1.063	0.0003
49	100	Unbiased-100krad	1.06	1.06	0
50	105	Biased-100krad	1.0582	1.0558	-0.0024
51	105	Biased-100krad	1.0626	1.06	-0.0026
52	105	Biased-100krad	1.0567	1.055	-0.0017
53	105	Biased-100krad	1.0593	1.0583	-0.001
54	105	Biased-100krad	1.0586	1.0566	-0.002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0583	1.0605	1.0629	0.0023116	1.0576	1.0602	1.0629	0.0026502	-0.0007	-0.00023333	0	0.00040415
30	1.0548	1.059	1.0623	0.0028351	1.0543	1.0586	1.062	0.0028657	-0.0009	-0.00046	-0.0003	0.00026077
35	1.058	1.0608	1.0628	0.0017958	1.0556	1.0595	1.0626	0.0027555	-0.003	-0.00126	-0.0002	0.0013334
50	1.0586	1.0602	1.0609	0.00091924	1.0587	1.0592	1.0604	0.00068337	-0.0021	-0.00098	0.0001	0.00087864
55	1.0592	1.0608	1.0639	0.0018676	1.0567	1.0591	1.0628	0.0025638	-0.0028	-0.00162	-0.0006	0.00096799
100	1.0556	1.0602	1.0627	0.0028831	1.0556	1.0592	1.063	0.0027943	-0.0026	-0.00094	0.0003	0.0014311
105	1.0567	1.0591	1.0626	0.0021856	1.055	1.0571	1.06	0.002012	-0.0026	-0.00194	-0.001	0.00063087

Device Test: 31.18 _PWRGD|FallingGood/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD





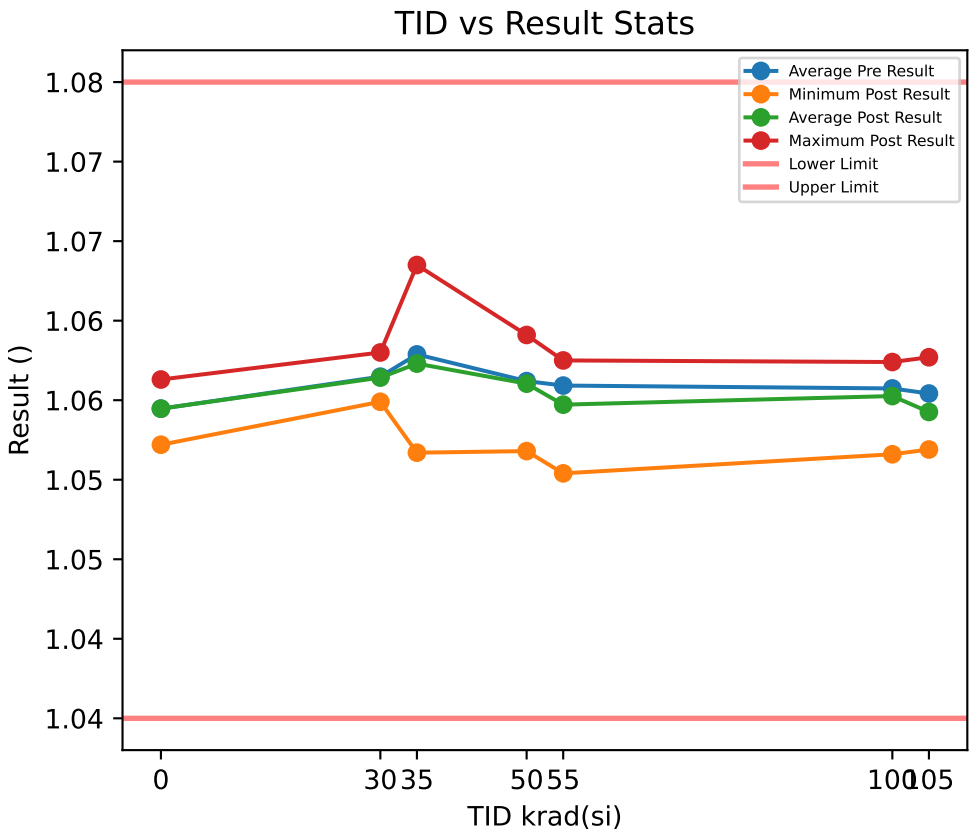
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

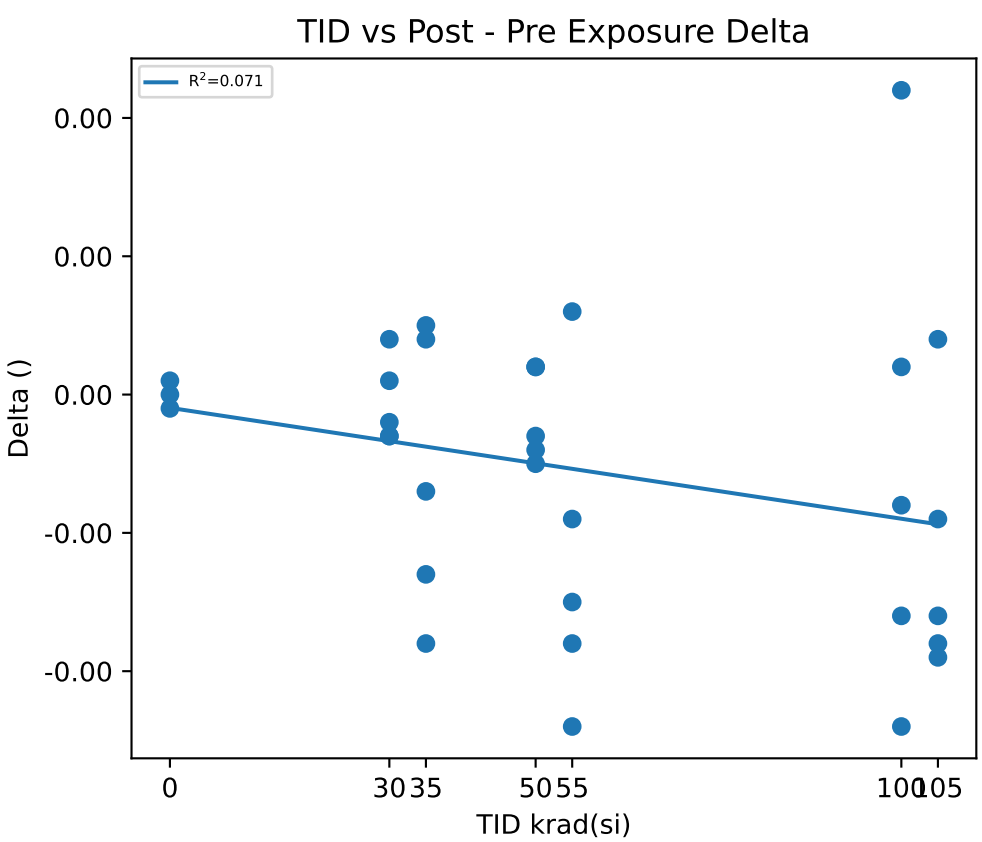
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0619	1.0619	0
2	0	CU2	1.0578	1.0578	0
3	0	CU3	1.0591	1.0591	0
11	30	Unbiased-30krad	1.0602	1.0599	-0.0003
12	30	Unbiased-30krad	1.0613	1.0592	-0.0021
13	30	Unbiased-30krad	1.0602	1.0591	-0.0011
14	30	Unbiased-30krad	1.058	1.0577	-0.0003
15	30	Unbiased-30krad	1.0614	1.0614	0
16	35	Biased-30krad	1.0613	1.0606	-0.0007
17	35	Biased-30krad	1.059	1.0584	-0.0006
18	35	Biased-30krad	1.0585	1.0582	-0.0003
19	35	Biased-30krad	1.0593	1.0582	-0.0011
20	35	Biased-30krad	1.0644	1.0632	-0.0012
30	50	Unbiased-50krad	1.0606	1.0599	-0.0007
31	50	Unbiased-50krad	1.0592	1.0578	-0.0014
32	50	Unbiased-50krad	1.0609	1.0604	-0.0005
33	50	Unbiased-50krad	1.0633	1.0631	-0.0002
34	50	Unbiased-50krad	1.0609	1.0604	-0.0005
40	55	Biased-50krad	1.063	1.0604	-0.0026
41	55	Biased-50krad	1.0565	1.0553	-0.0012
42	55	Biased-50krad	1.0608	1.0583	-0.0025
43	55	Biased-50krad	1.0645	1.0643	-0.0002
44	55	Biased-50krad	1.0613	1.058	-0.0033
45	100	Unbiased-100krad	1.0639	1.0621	-0.0018
46	100	Unbiased-100krad	1.0631	1.0641	0.001
47	100	Unbiased-100krad	1.0612	1.0607	-0.0005
48	100	Unbiased-100krad	1.0601	1.0586	-0.0015
49	100	Unbiased-100krad	1.0586	1.0577	-0.0009
50	105	Biased-100krad	1.0641	1.0611	-0.003
51	105	Biased-100krad	1.0618	1.0584	-0.0034
52	105	Biased-100krad	1.0611	1.0592	-0.0019
53	105	Biased-100krad	1.0628	1.0583	-0.0045
54	105	Biased-100krad	1.0622	1.0596	-0.0026

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0578	1.0596	1.0619	0.0020952	1.0578	1.0596	1.0619	0.0020952	0	0	0	0
30	1.058	1.0602	1.0614	0.0013682	1.0577	1.0595	1.0614	0.0013465	-0.0021	-0.00076	0	0.00085323
35	1.0585	1.0605	1.0644	0.0024259	1.0582	1.0597	1.0632	0.0021936	-0.0012	-0.00078	-0.0003	0.00037014
50	1.0592	1.061	1.0633	0.0014755	1.0578	1.0603	1.0631	0.0018887	-0.0014	-0.00066	-0.0002	0.00045056
55	1.0565	1.0612	1.0645	0.0030161	1.0553	1.0593	1.0643	0.0033501	-0.0033	-0.00196	-0.0002	0.0012422
100	1.0586	1.0614	1.0639	0.0021626	1.0577	1.0606	1.0641	0.0025938	-0.0018	-0.00074	0.001	0.0010968
105	1.0611	1.0624	1.0641	0.0011336	1.0583	1.0593	1.0611	0.0011345	-0.0045	-0.00308	-0.0019	0.00096799

Device Test: 31.19 _PWRGD|FallingGood/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD





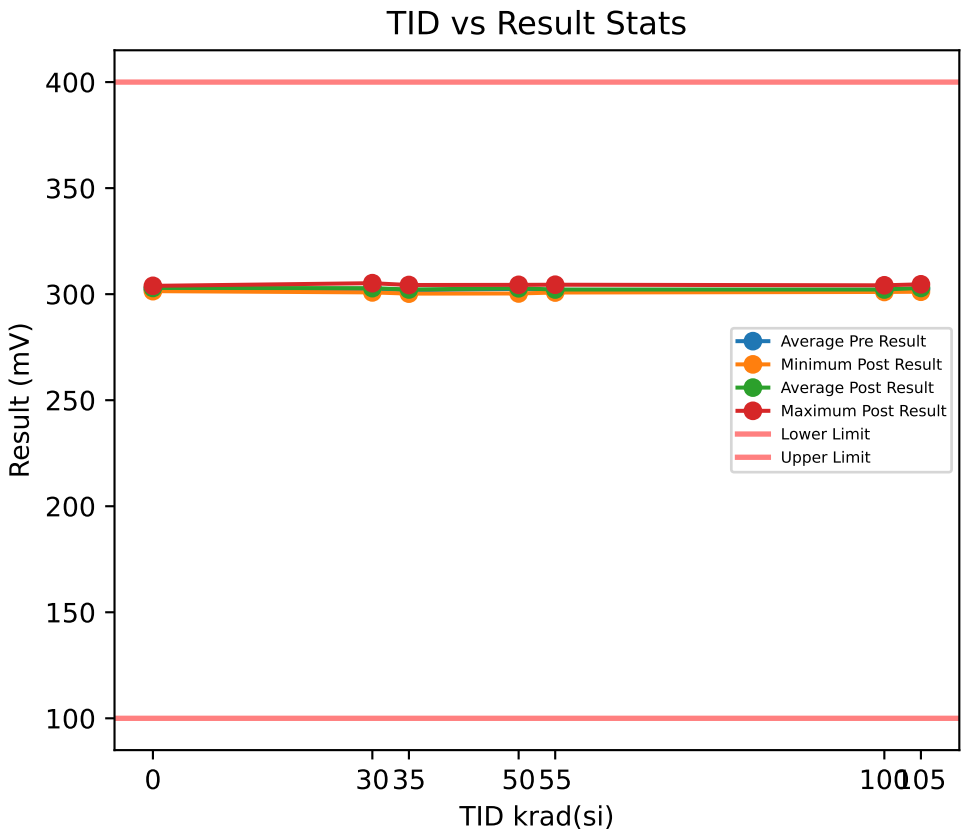
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

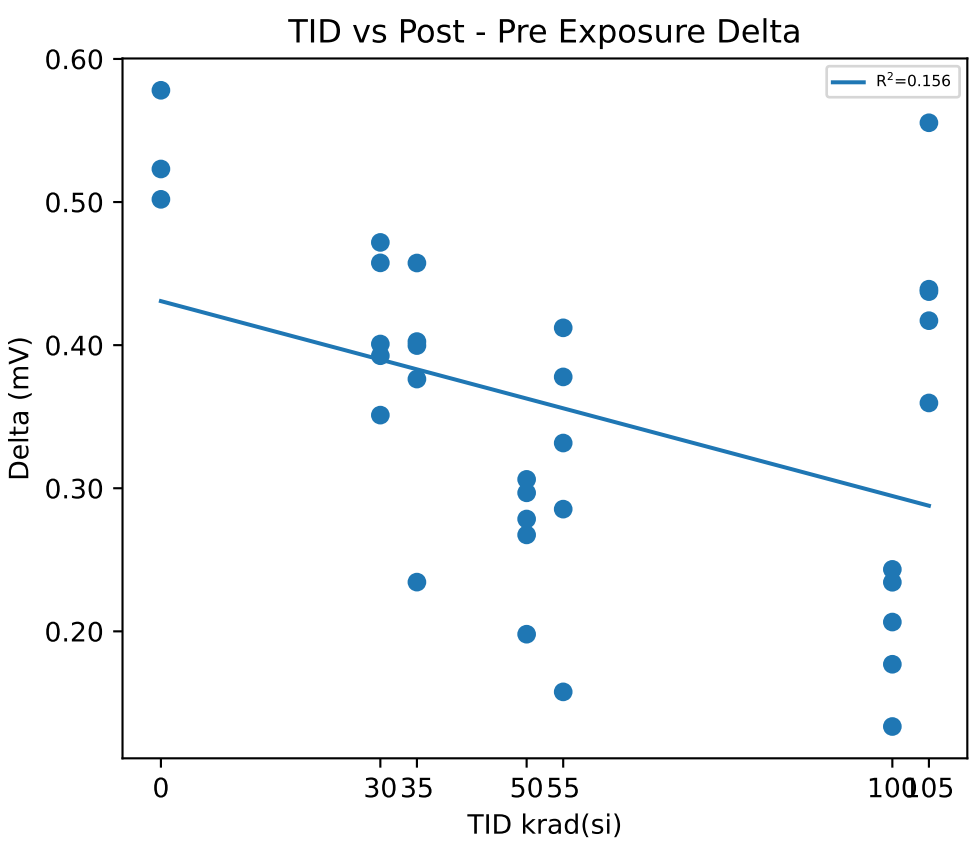
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0613	1.0613	0
2	0	CU2	1.0598	1.0599	0.0001
3	0	CU3	1.0573	1.0572	-0.0001
11	30	Unbiased-30krad	1.0632	1.063	-0.0002
12	30	Unbiased-30krad	1.0621	1.0625	0.0004
13	30	Unbiased-30krad	1.0616	1.0613	-0.0003
14	30	Unbiased-30krad	1.0607	1.0604	-0.0003
15	30	Unbiased-30krad	1.0598	1.0599	0.0001
16	35	Biased-30krad	1.0613	1.0606	-0.0007
17	35	Biased-30krad	1.0665	1.0652	-0.0013
18	35	Biased-30krad	1.0562	1.0567	0.0005
19	35	Biased-30krad	1.0703	1.0685	-0.0018
20	35	Biased-30krad	1.0601	1.0605	0.0004
30	50	Unbiased-50krad	1.0639	1.0641	0.0002
31	50	Unbiased-50krad	1.0626	1.0621	-0.0005
32	50	Unbiased-50krad	1.0617	1.0613	-0.0004
33	50	Unbiased-50krad	1.0612	1.0609	-0.0003
34	50	Unbiased-50krad	1.0566	1.0568	0.0002
40	55	Biased-50krad	1.0643	1.0625	-0.0018
41	55	Biased-50krad	1.0595	1.0601	0.0006
42	55	Biased-50krad	1.0578	1.0554	-0.0024
43	55	Biased-50krad	1.0603	1.0594	-0.0009
44	55	Biased-50krad	1.0627	1.0612	-0.0015
45	100	Unbiased-100krad	1.0573	1.0595	0.0022
46	100	Unbiased-100krad	1.0632	1.0624	-0.0008
47	100	Unbiased-100krad	1.059	1.0566	-0.0024
48	100	Unbiased-100krad	1.0611	1.0613	0.0002
49	100	Unbiased-100krad	1.0631	1.0615	-0.0016
50	105	Biased-100krad	1.0569	1.0573	0.0004
51	105	Biased-100krad	1.0612	1.0603	-0.0009
52	105	Biased-100krad	1.0643	1.0627	-0.0016
53	105	Biased-100krad	1.0588	1.0569	-0.0019
54	105	Biased-100krad	1.0609	1.0591	-0.0018

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0573	1.0595	1.0613	0.0020207	1.0572	1.0595	1.0613	0.0020841	-0.0001	0	0.0001	0.0001
30	1.0598	1.0615	1.0632	0.0013027	1.0599	1.0614	1.063	0.0013255	-0.0003	-6e-05	0.0004	0.00030496
35	1.0562	1.0629	1.0703	0.0055454	1.0567	1.0623	1.0685	0.0045918	-0.0018	-0.00058	0.0005	0.0010183
50	1.0566	1.0612	1.0639	0.0027686	1.0568	1.061	1.0641	0.0026717	-0.0005	-0.00016	0.0002	0.00033615
55	1.0578	1.0609	1.0643	0.002585	1.0554	1.0597	1.0625	0.0026846	-0.0024	-0.0012	0.0006	0.0011424
100	1.0573	1.0607	1.0632	0.0025793	1.0566	1.0603	1.0624	0.0023007	-0.0024	-0.00048	0.0022	0.001781
105	1.0569	1.0604	1.0643	0.0027797	1.0569	1.0593	1.0627	0.0023639	-0.0019	-0.00116	0.0004	0.00095551

Device Test: 31.2 _PWRGD|VOL/PWRGD2/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW





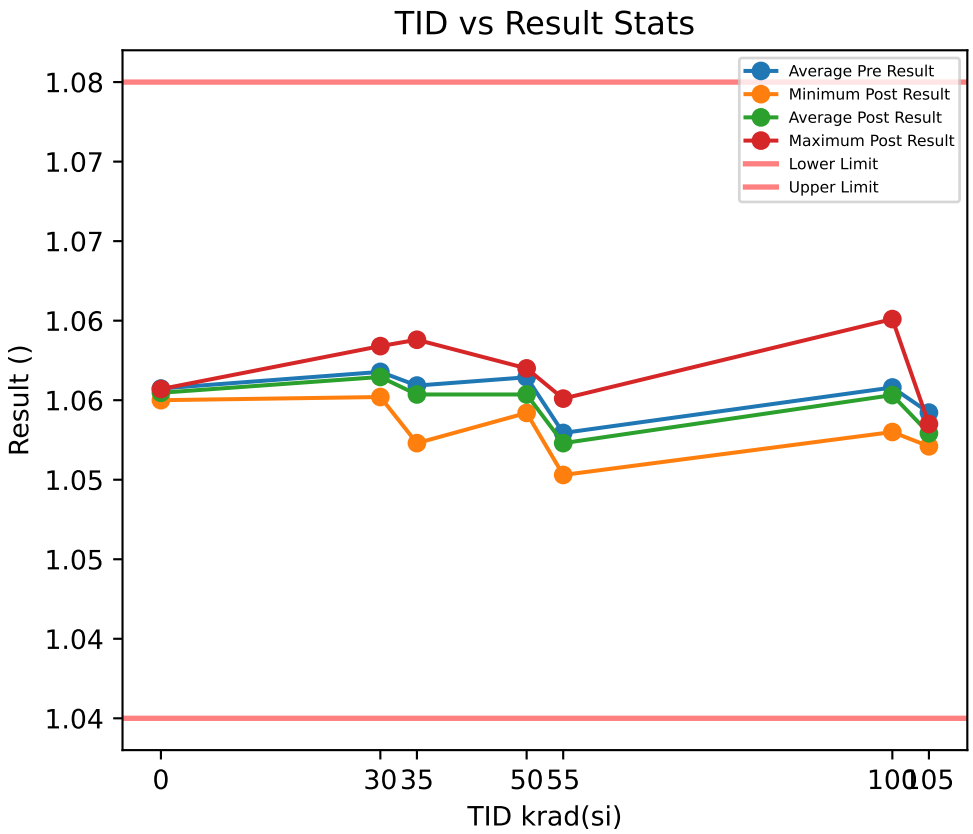
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

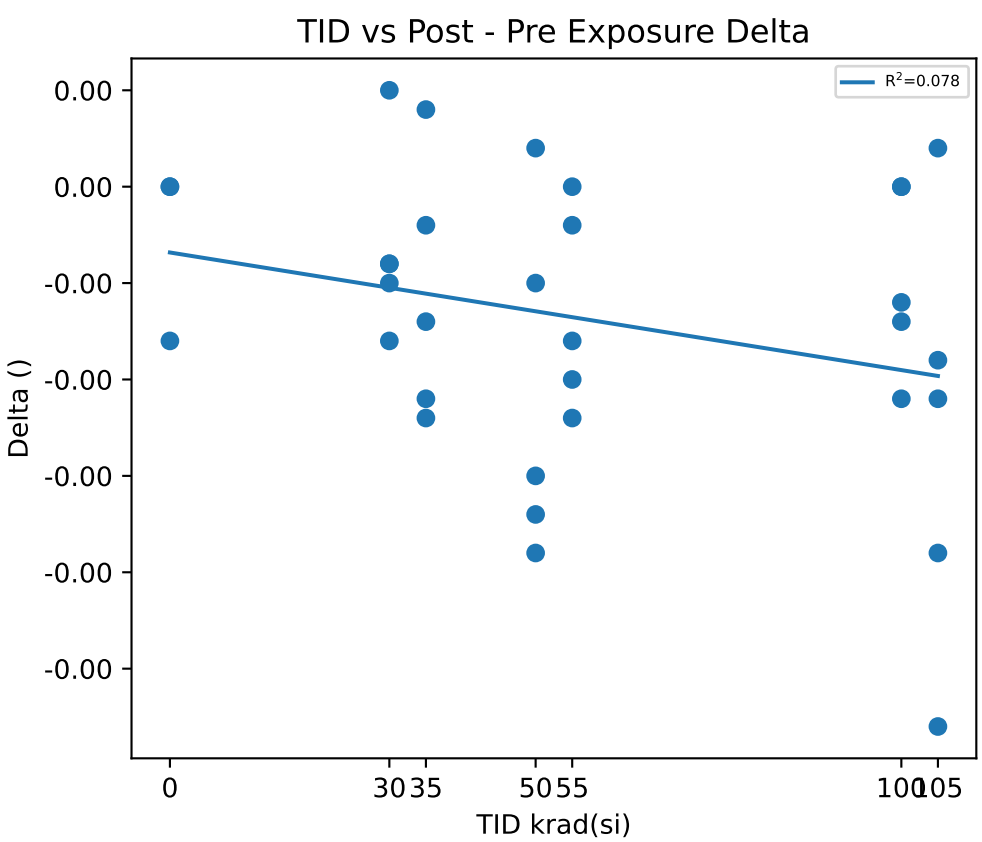
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	302.87	303.45	0.5781
2	0	CU2	300.91	301.41	0.5019
3	0	CU3	303.4	303.92	0.5231
11	30	Unbiased-30krad	300.51	300.86	0.3511
12	30	Unbiased-30krad	303.65	304.04	0.3926
13	30	Unbiased-30krad	300.42	300.82	0.4008
14	30	Unbiased-30krad	302.82	303.29	0.4718
15	30	Unbiased-30krad	304.72	305.18	0.4575
16	35	Biased-30krad	303.33	303.79	0.4574
17	35	Biased-30krad	301.98	302.35	0.3763
18	35	Biased-30krad	303.91	304.32	0.4025
19	35	Biased-30krad	299.94	300.34	0.3997
20	35	Biased-30krad	300.02	300.25	0.2344
30	50	Unbiased-50krad	302.94	303.21	0.2785
31	50	Unbiased-50krad	300.02	300.32	0.3062
32	50	Unbiased-50krad	303.28	303.48	0.198
33	50	Unbiased-50krad	302.17	302.44	0.2674
34	50	Unbiased-50krad	304.09	304.39	0.2968
40	55	Biased-50krad	300.48	300.77	0.2854
41	55	Biased-50krad	301.32	301.7	0.3778
42	55	Biased-50krad	304.04	304.45	0.4121
43	55	Biased-50krad	302.92	303.25	0.3316
44	55	Biased-50krad	300.65	300.81	0.1577
45	100	Unbiased-100krad	300.86	301.03	0.177
46	100	Unbiased-100krad	302.74	302.97	0.2343
47	100	Unbiased-100krad	300.96	301.09	0.1335
48	100	Unbiased-100krad	301.53	301.74	0.2065
49	100	Unbiased-100krad	303.93	304.18	0.2433
50	105	Biased-100krad	303.54	303.98	0.4391
51	105	Biased-100krad	300.73	301.15	0.4171
52	105	Biased-100krad	302.48	303.03	0.5554
53	105	Biased-100krad	301.39	301.82	0.4374
54	105	Biased-100krad	304.28	304.64	0.3596

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	300.91	302.39	303.4	1.3097	301.41	302.93	303.92	1.3321	0.5019	0.53437	0.5781	0.03933
30	300.42	302.42	304.72	1.9104	300.82	302.84	305.18	1.9426	0.3511	0.41476	0.4718	0.049545
35	299.94	301.84	303.91	1.8346	300.25	302.21	304.32	1.8888	0.2344	0.37406	0.4574	0.083549
50	300.02	302.5	304.09	1.5505	300.32	302.77	304.39	1.5351	0.198	0.26938	0.3062	0.04269
55	300.48	301.88	304.04	1.5422	300.77	302.19	304.45	1.613	0.1577	0.31292	0.4121	0.099053
100	300.86	302	303.93	1.3121	301.03	302.2	304.18	1.3507	0.1335	0.19892	0.2433	0.04483
105	300.73	302.48	304.28	1.4682	301.15	302.92	304.64	1.4522	0.3596	0.44172	0.5554	0.071236

Device Test: 31.20 _PWRGD|FallingGood/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_GOOD





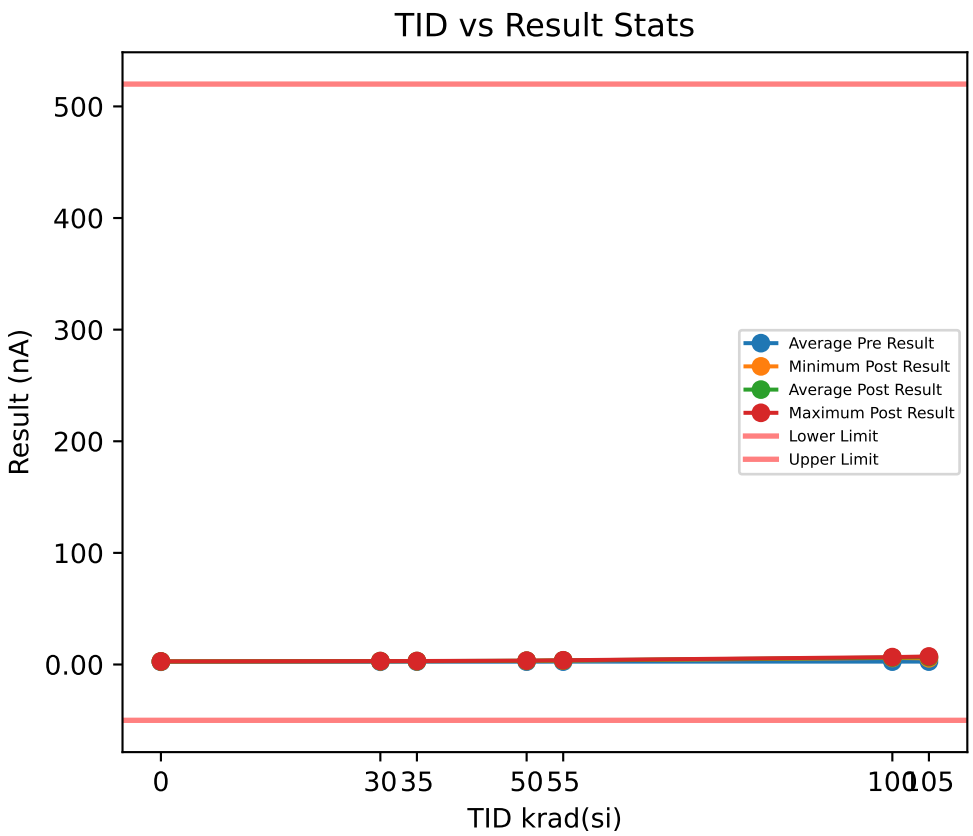
Test Results (Lower Limit = 1.04, Upper Limit = 1.08 ())

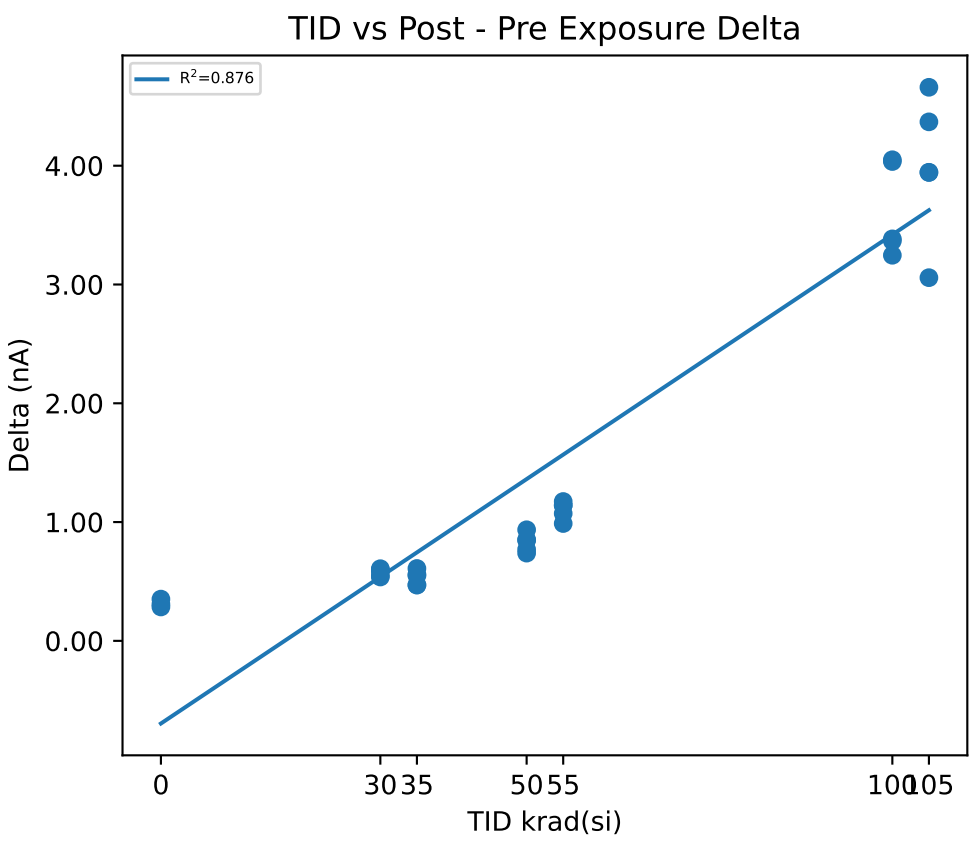
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0607	1.0607	0
2	0	CU2	1.0615	1.0607	-0.0008
3	0	CU3	1.06	1.06	0
11	30	Unbiased-30krad	1.0606	1.0602	-0.0004
12	30	Unbiased-30krad	1.0623	1.0618	-0.0005
13	30	Unbiased-30krad	1.061	1.0606	-0.0004
14	30	Unbiased-30krad	1.0629	1.0634	0.0005
15	30	Unbiased-30krad	1.0621	1.0613	-0.0008
16	35	Biased-30krad	1.0611	1.0604	-0.0007
17	35	Biased-30krad	1.0594	1.0598	0.0004
18	35	Biased-30krad	1.064	1.0638	-0.0002
19	35	Biased-30krad	1.0616	1.0605	-0.0011
20	35	Biased-30krad	1.0585	1.0573	-0.0012
30	50	Unbiased-50krad	1.0621	1.0604	-0.0017
31	50	Unbiased-50krad	1.0607	1.0592	-0.0015
32	50	Unbiased-50krad	1.0595	1.0597	0.0002
33	50	Unbiased-50krad	1.0639	1.062	-0.0019
34	50	Unbiased-50krad	1.061	1.0605	-0.0005
40	55	Biased-50krad	1.0603	1.0601	-0.0002
41	55	Biased-50krad	1.0576	1.0566	-0.001
42	55	Biased-50krad	1.0561	1.0553	-0.0008
43	55	Biased-50krad	1.0572	1.056	-0.0012
44	55	Biased-50krad	1.0585	1.0585	0
45	100	Unbiased-100krad	1.0596	1.0585	-0.0011
46	100	Unbiased-100krad	1.06	1.06	0
47	100	Unbiased-100krad	1.0657	1.0651	-0.0006
48	100	Unbiased-100krad	1.0587	1.058	-0.0007
49	100	Unbiased-100krad	1.06	1.06	0
50	105	Biased-100krad	1.0579	1.0581	0.0002
51	105	Biased-100krad	1.0588	1.0579	-0.0009
52	105	Biased-100krad	1.0599	1.0571	-0.0028
53	105	Biased-100krad	1.0596	1.0585	-0.0011
54	105	Biased-100krad	1.0599	1.058	-0.0019

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.06	1.0607	1.0615	0.00075056	1.06	1.0605	1.0607	0.00040415	-0.0008	-0.00026667	0	0.00046188
30	1.0606	1.0618	1.0629	0.00095237	1.0602	1.0615	1.0634	0.0012482	-0.0008	-0.00032	0.0005	0.00048683
35	1.0585	1.0609	1.064	0.00213	1.0573	1.0604	1.0638	0.0023201	-0.0012	-0.00056	0.0004	0.00066558
50	1.0595	1.0614	1.0639	0.0016577	1.0592	1.0604	1.062	0.0010597	-0.0019	-0.00108	0.0002	0.00089554
55	1.0561	1.0579	1.0603	0.0015758	1.0553	1.0573	1.0601	0.001966	-0.0012	-0.00064	0	0.00051769
100	1.0587	1.0608	1.0657	0.0027902	1.058	1.0603	1.0651	0.0028173	-0.0011	-0.00048	0	0.00047645
105	1.0579	1.0592	1.0599	0.00086429	1.0571	1.0579	1.0585	0.00051186	-0.0028	-0.0013	0.0002	0.0011247

Device Test: 31.21 _PWRGD|LeakageHigh/PWRGD1/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HIGH_LEAK





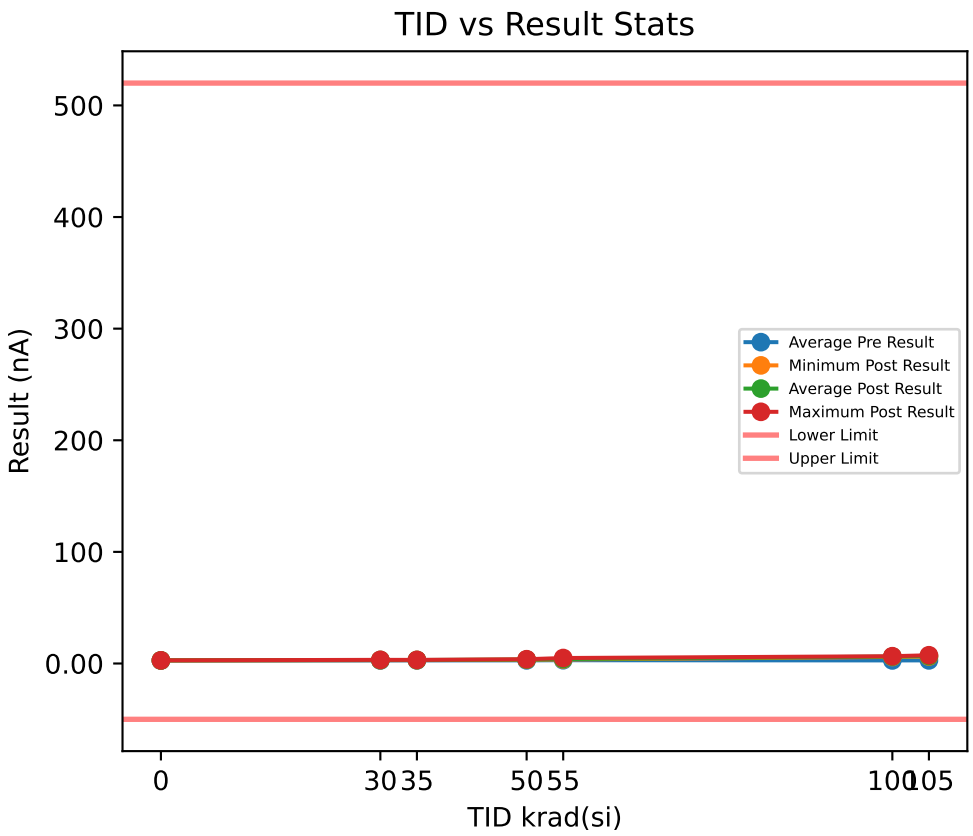
Test Results (Lower Limit = -50.0, Upper Limit = 520.0 (nA))

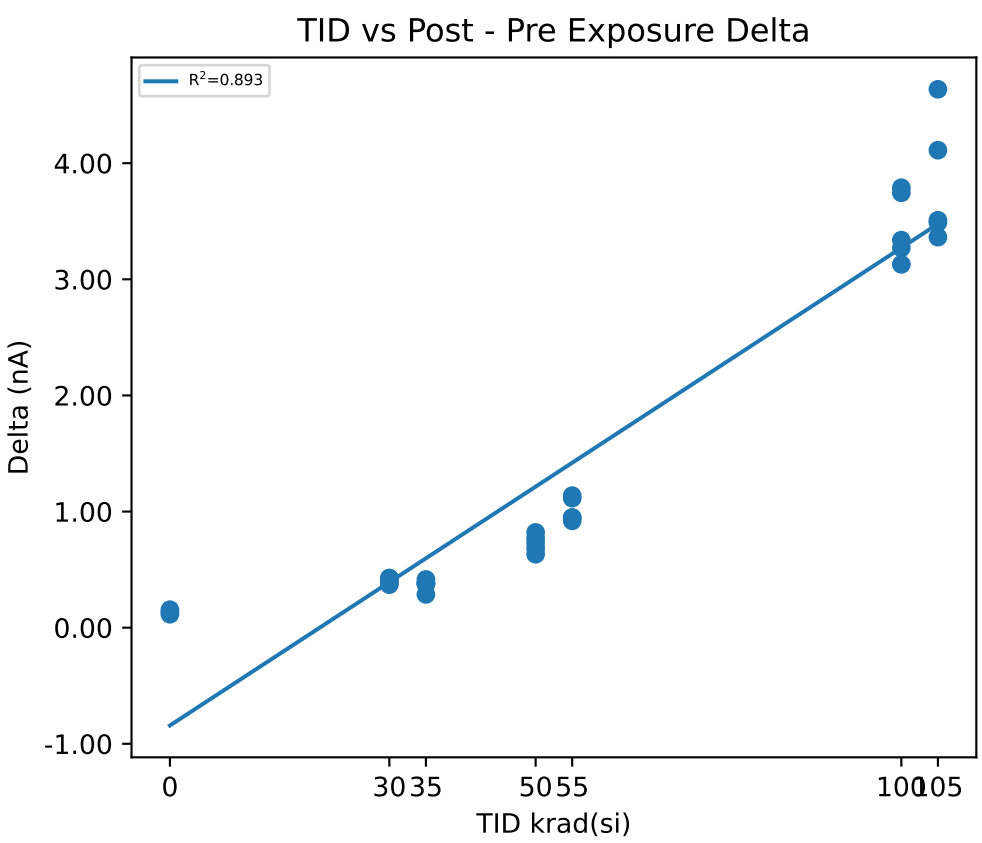
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4612	2.769	0.3078
2	0	CU2	2.4162	2.7677	0.3515
3	0	CU3	2.3981	2.6835	0.2854
11	30	Unbiased-30krad	2.4518	3.0512	0.5994
12	30	Unbiased-30krad	2.4843	3.0219	0.5376
13	30	Unbiased-30krad	2.4418	3.0493	0.6075
14	30	Unbiased-30krad	2.3994	2.9856	0.5862
15	30	Unbiased-30krad	2.4031	2.9532	0.5501
16	35	Biased-30krad	2.4874	3.0462	0.5588
17	35	Biased-30krad	2.488	2.9575	0.4695
18	35	Biased-30krad	2.5249	2.9963	0.4714
19	35	Biased-30krad	2.5161	3.1255	0.6094
20	35	Biased-30krad	2.5342	3.0837	0.5495
30	50	Unbiased-50krad	2.538	3.3915	0.8535
31	50	Unbiased-50krad	2.5823	3.4277	0.8454
32	50	Unbiased-50krad	2.4855	3.2554	0.7699
33	50	Unbiased-50krad	2.5348	3.4701	0.9353
34	50	Unbiased-50krad	2.4787	3.2173	0.7386
40	55	Biased-50krad	2.6123	3.7536	1.1413
41	55	Biased-50krad	2.6016	3.5894	0.9878
42	55	Biased-50krad	2.4443	3.5163	1.072
43	55	Biased-50krad	2.5517	3.6924	1.1407
44	55	Biased-50krad	2.6222	3.7954	1.1732
45	100	Unbiased-100krad	2.6447	5.8908	3.2461
46	100	Unbiased-100krad	2.5579	5.942	3.3841
47	100	Unbiased-100krad	2.5548	6.59	4.0352
48	100	Unbiased-100krad	2.5711	6.6213	4.0502
49	100	Unbiased-100krad	2.548	5.9145	3.3665
50	105	Biased-100krad	2.4705	5.528	3.0575
51	105	Biased-100krad	2.8114	6.7561	3.9447
52	105	Biased-100krad	2.5692	6.9384	4.3692
53	105	Biased-100krad	2.5567	7.2169	4.6602
54	105	Biased-100krad	2.5511	6.4945	3.9434

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3981	2.4252	2.4612	0.032492	2.6835	2.7401	2.769	0.048992	0.2854	0.3149	0.3515	0.033617
30	2.3994	2.4361	2.4843	0.03549	2.9532	3.0122	3.0512	0.042368	0.5376	0.57616	0.6075	0.030778
35	2.4874	2.5101	2.5342	0.021445	2.9575	3.0418	3.1255	0.067003	0.4695	0.53172	0.6094	0.060402
50	2.4787	2.5239	2.5823	0.042561	3.2173	3.3524	3.4701	0.11036	0.7386	0.82854	0.9353	0.077189
55	2.4443	2.5664	2.6222	0.073457	3.5163	3.6694	3.7954	0.11547	0.9878	1.103	1.1732	0.074243
100	2.548	2.5753	2.6447	0.039694	5.8908	6.1917	6.6213	0.37846	3.2461	3.6164	4.0502	0.39278
105	2.4705	2.5918	2.8114	0.12878	5.528	6.5868	7.2169	0.64786	3.0575	3.995	4.6602	0.60552

Device Test: 31.22 _PWRGD|LeakageHigh/PWRGD2/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HIGH_LEAK





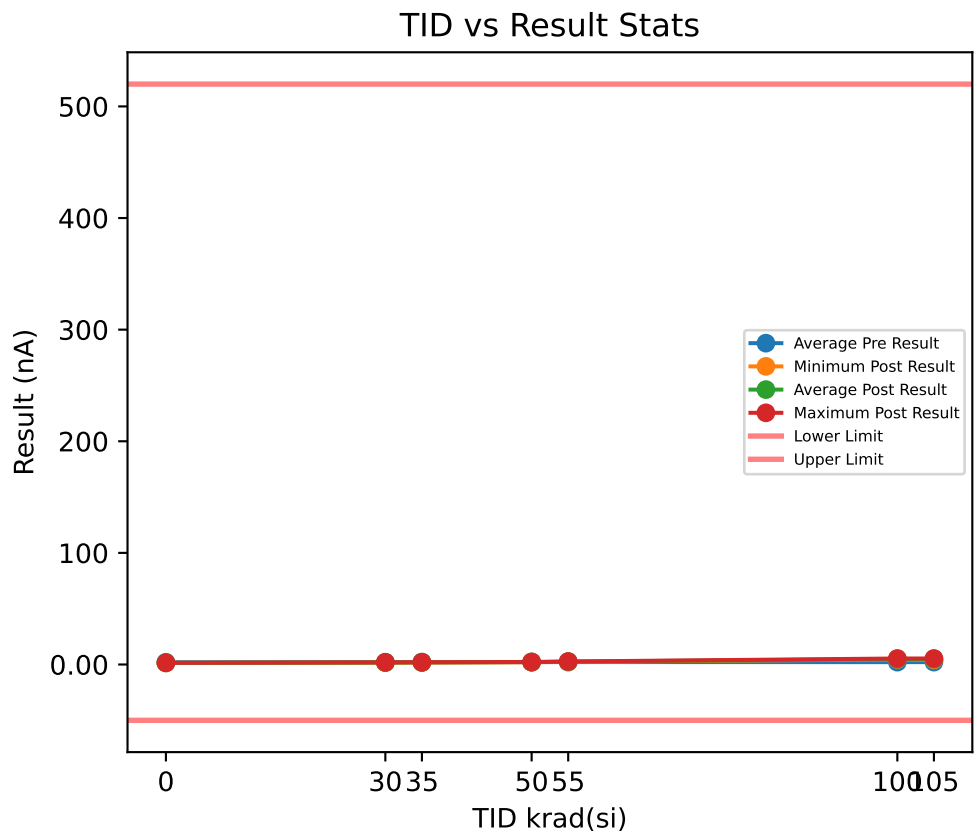
Test Results (Lower Limit = -50.0, Upper Limit = 520.0 (nA))

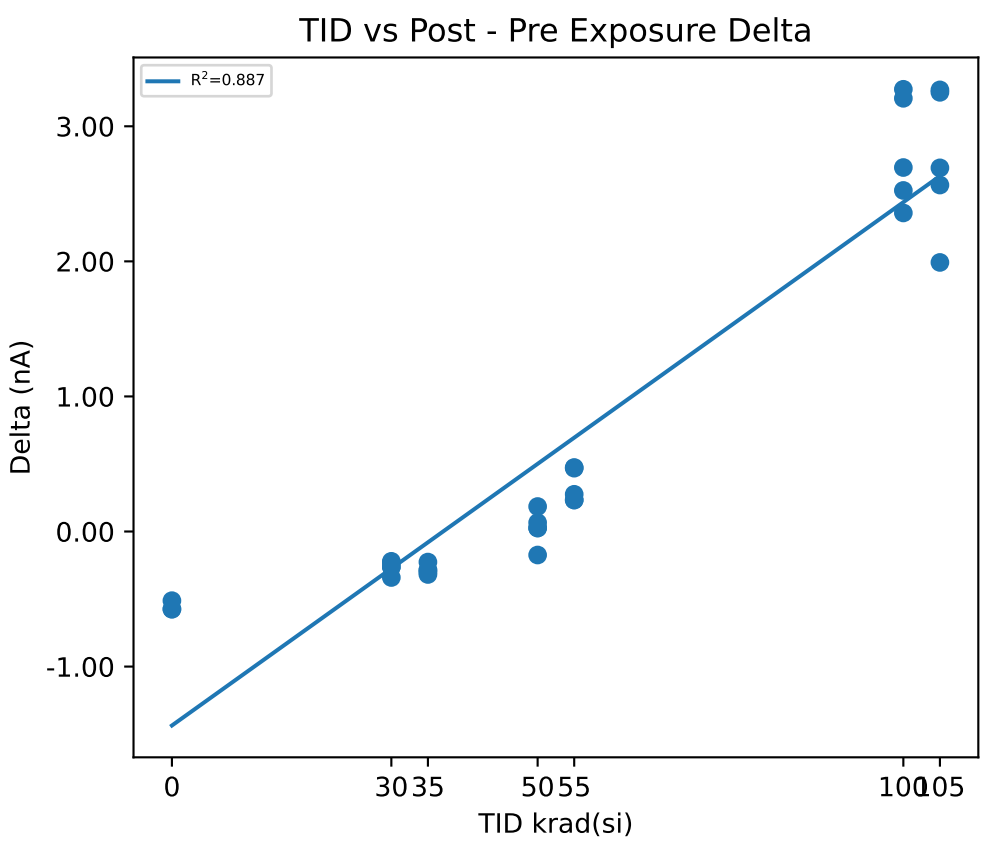
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.6856	2.8161	0.1305
2	0	CU2	2.6088	2.7637	0.1549
3	0	CU3	2.6787	2.7943	0.1156
11	30	Unbiased-30krad	2.8667	3.2662	0.3995
12	30	Unbiased-30krad	2.6956	3.0846	0.389
13	30	Unbiased-30krad	2.7118	3.1389	0.4271
14	30	Unbiased-30krad	2.6931	3.0633	0.3702
15	30	Unbiased-30krad	2.5957	3.0221	0.4264
16	35	Biased-30krad	2.8011	3.1776	0.3765
17	35	Biased-30krad	2.7212	3.0078	0.2866
18	35	Biased-30krad	2.7306	3.112	0.3814
19	35	Biased-30krad	2.8167	3.2319	0.4152
20	35	Biased-30krad	2.7574	3.1389	0.3815
30	50	Unbiased-50krad	3.1482	3.8305	0.6823
31	50	Unbiased-50krad	2.7068	3.5272	0.8204
32	50	Unbiased-50krad	2.6887	3.4142	0.7255
33	50	Unbiased-50krad	2.7331	3.5034	0.7703
34	50	Unbiased-50krad	2.7518	3.3842	0.6324
40	55	Biased-50krad	2.7674	3.7144	0.947
41	55	Biased-50krad	2.7106	3.6595	0.9489
42	55	Biased-50krad	2.655	3.5752	0.9202
43	55	Biased-50krad	2.7412	3.878	1.1368
44	55	Biased-50krad	3.8032	4.9186	1.1154
45	100	Unbiased-100krad	2.7593	6.0298	3.2705
46	100	Unbiased-100krad	2.7961	6.1334	3.3373
47	100	Unbiased-100krad	2.7867	6.5317	3.745
48	100	Unbiased-100krad	2.6531	6.4418	3.7887
49	100	Unbiased-100krad	2.7387	5.8675	3.1288
50	105	Biased-100krad	2.8479	6.2108	3.3629
51	105	Biased-100krad	2.9004	6.3893	3.4889
52	105	Biased-100krad	2.7374	6.8494	4.112
53	105	Biased-100krad	2.758	7.3944	4.6364
54	105	Biased-100krad	2.7093	6.2183	3.509

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6088	2.6577	2.6856	0.042489	2.7637	2.7914	2.8161	0.026323	0.1156	0.13367	0.1549	0.01984
30	2.5957	2.7126	2.8667	0.097573	3.0221	3.115	3.2662	0.094419	0.3702	0.40244	0.4271	0.02455
35	2.7212	2.7654	2.8167	0.042234	3.0078	3.1336	3.2319	0.083545	0.2866	0.36824	0.4152	0.048186
50	2.6887	2.8057	3.1482	0.19297	3.3842	3.5319	3.8305	0.17725	0.6324	0.72618	0.8204	0.07339
55	2.655	2.9355	3.8032	0.48687	3.5752	3.9491	4.9186	0.55311	0.9202	1.0137	1.1368	0.10355
100	2.6531	2.7468	2.7961	0.057061	5.8675	6.2008	6.5317	0.27949	3.1288	3.4541	3.7887	0.2957
105	2.7093	2.7906	2.9004	0.080377	6.2108	6.6124	7.3944	0.50844	3.3629	3.8218	4.6364	0.54015

Device Test: 31.23 _PWRGD|LeakageHigh/PWRGD3/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HIGH_LEAK





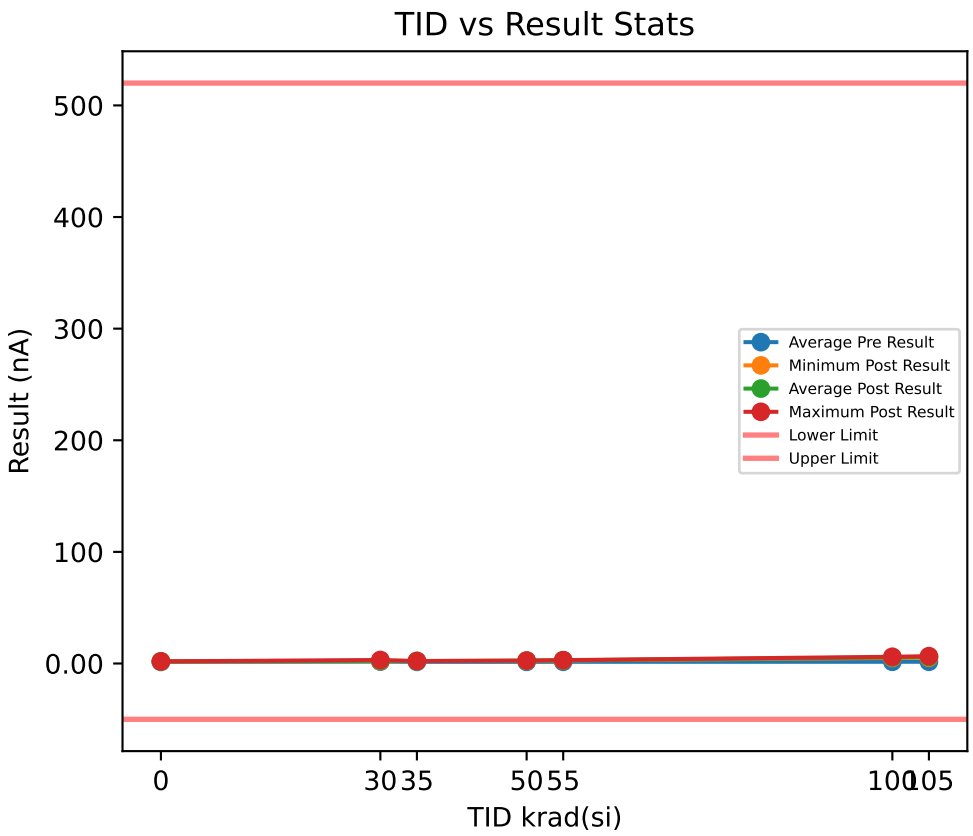
Test Results (Lower Limit = -50.0, Upper Limit = 520.0 (nA))

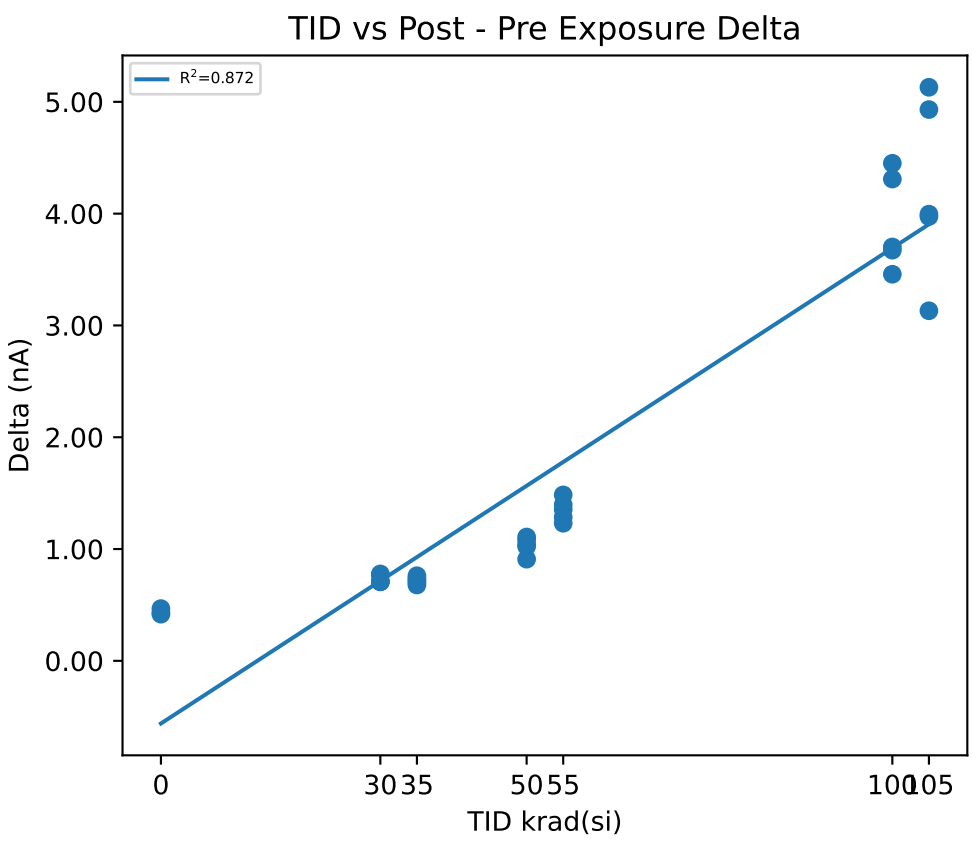
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0109	1.4352	-0.5757
2	0	CU2	2.0084	1.4964	-0.512
3	0	CU3	2.029	1.4558	-0.5732
11	30	Unbiased-30krad	2.079	1.7385	-0.3405
12	30	Unbiased-30krad	2.0465	1.7828	-0.2637
13	30	Unbiased-30krad	2.1027	1.882	-0.2207
14	30	Unbiased-30krad	2.1645	1.9326	-0.2319
15	30	Unbiased-30krad	1.941	1.6792	-0.2618
16	35	Biased-30krad	2.1015	1.7834	-0.3181
17	35	Biased-30krad	2.1776	1.8745	-0.3031
18	35	Biased-30krad	2.0965	1.8134	-0.2831
19	35	Biased-30krad	2.1901	1.9638	-0.2263
20	35	Biased-30krad	2.2969	2.0093	-0.2876
30	50	Unbiased-50krad	2.1883	2.2146	0.0263
31	50	Unbiased-50krad	2.059	2.244	0.185
32	50	Unbiased-50krad	2.0896	2.1154	0.0258
33	50	Unbiased-50krad	2.1658	2.2315	0.0657
34	50	Unbiased-50krad	2.2301	2.0561	-0.174
40	55	Biased-50krad	2.1895	2.4231	0.2336
41	55	Biased-50krad	2.3206	2.5535	0.2329
42	55	Biased-50krad	2.0933	2.3688	0.2755
43	55	Biased-50krad	2.2126	2.6864	0.4738
44	55	Biased-50krad	2.1595	2.6284	0.4689
45	100	Unbiased-100krad	2.0734	4.5984	2.525
46	100	Unbiased-100krad	2.1346	4.8293	2.6947
47	100	Unbiased-100krad	2.0996	5.3735	3.2739
48	100	Unbiased-100krad	2.0659	5.273	3.2071
49	100	Unbiased-100krad	2.1533	4.5117	2.3584
50	105	Biased-100krad	2.0877	4.0798	1.9921
51	105	Biased-100krad	2.2126	4.9048	2.6922
52	105	Biased-100krad	2.1302	5.3816	3.2514
53	105	Biased-100krad	2.1202	5.3897	3.2695
54	105	Biased-100krad	2.1514	4.7164	2.565

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0084	2.0161	2.029	0.011241	1.4352	1.4625	1.4964	0.03114	-0.5757	-0.55363	-0.512	0.036077
30	1.941	2.0667	2.1645	0.082493	1.6792	1.803	1.9326	0.1036	-0.3405	-0.26372	-0.2207	0.046803
35	2.0965	2.1725	2.2969	0.081591	1.7834	1.8889	2.0093	0.096364	-0.3181	-0.28364	-0.2263	0.034893
50	2.059	2.1466	2.2301	0.070715	2.0561	2.1723	2.244	0.082424	-0.174	0.02576	0.185	0.12928
55	2.0933	2.1951	2.3206	0.083244	2.3688	2.532	2.6864	0.13425	0.2329	0.33694	0.4738	0.12392
100	2.0659	2.1054	2.1533	0.037964	4.5117	4.9172	5.3735	0.39006	2.3584	2.8118	3.2739	0.40968
105	2.0877	2.1404	2.2126	0.046431	4.0798	4.8945	5.3897	0.54269	1.9921	2.754	3.2695	0.53225

Device Test: 31.24 _PWRGD|LeakageHigh/PWRGD4/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HIGH_LEAK





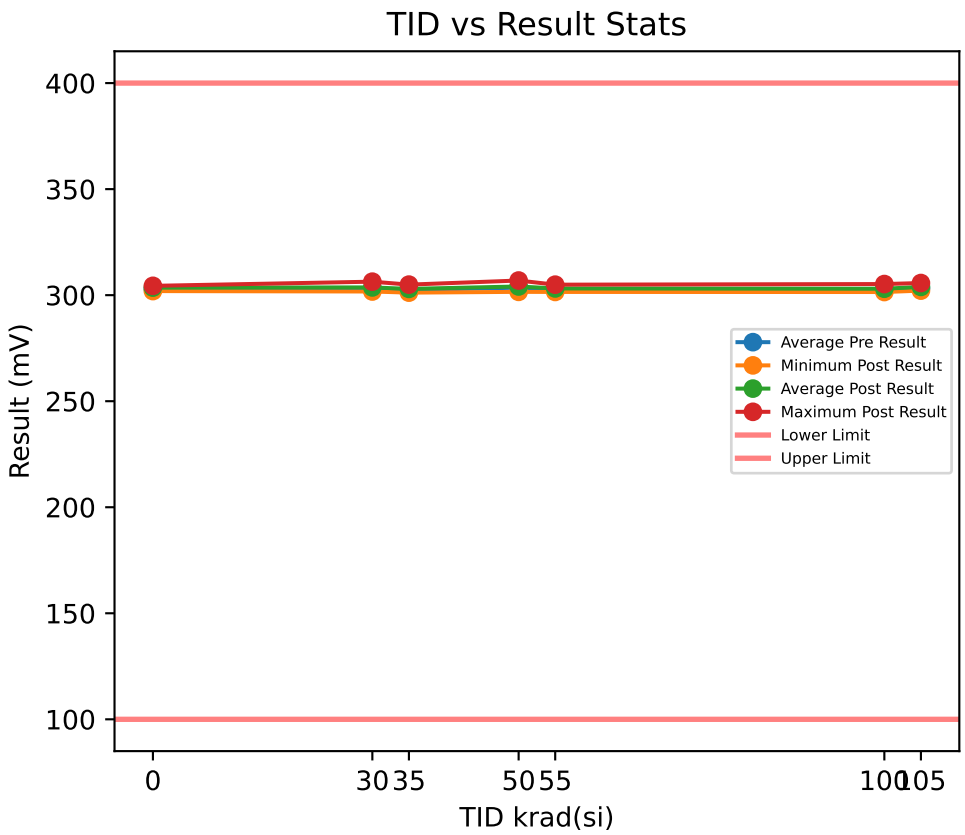
Test Results (Lower Limit = -50.0, Upper Limit = 520.0 (nA))

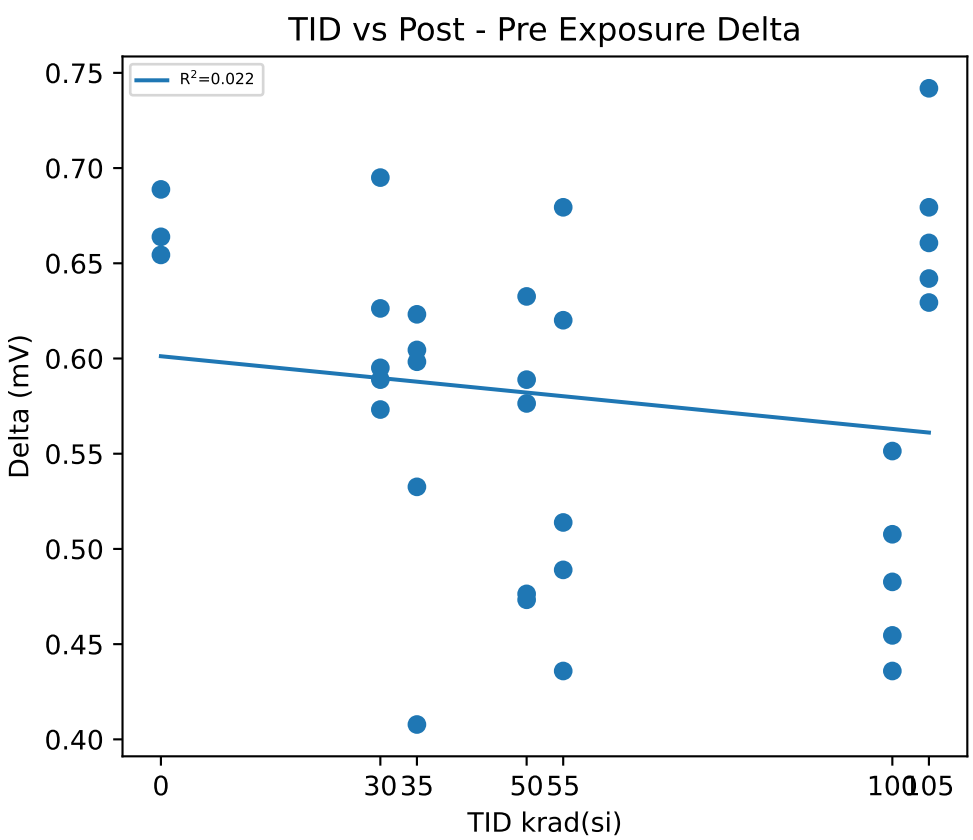
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.4825	1.9142	0.4317
2	0	CU2	1.4082	1.8755	0.4673
3	0	CU3	1.3901	1.8075	0.4174
11	30	Unbiased-30krad	1.4487	2.1595	0.7108
12	30	Unbiased-30krad	1.4107	2.1171	0.7064
13	30	Unbiased-30krad	1.5162	2.2825	0.7663
14	30	Unbiased-30krad	1.4288	2.2063	0.7775
15	30	Unbiased-30krad	2.4583	3.1657	0.7074
16	35	Biased-30krad	1.4662	2.1445	0.6783
17	35	Biased-30krad	1.4356	2.1352	0.6996
18	35	Biased-30krad	1.4768	2.1951	0.7183
19	35	Biased-30krad	1.4787	2.24	0.7613
20	35	Biased-30krad	1.4462	2.1807	0.7345
30	50	Unbiased-50krad	1.4993	2.5365	1.0372
31	50	Unbiased-50krad	1.3944	2.5022	1.1078
32	50	Unbiased-50krad	1.5087	2.5322	1.0235
33	50	Unbiased-50krad	1.5667	2.6464	1.0797
34	50	Unbiased-50krad	1.4238	2.3331	0.9093
40	55	Biased-50krad	1.5043	2.7887	1.2844
41	55	Biased-50krad	1.5212	2.7519	1.2307
42	55	Biased-50krad	1.4025	2.7556	1.3531
43	55	Biased-50krad	1.6217	3.0184	1.3967
44	55	Biased-50krad	1.5099	2.9941	1.4842
45	100	Unbiased-100krad	1.4637	4.9216	3.4579
46	100	Unbiased-100krad	1.6442	5.3461	3.7019
47	100	Unbiased-100krad	1.5873	6.0377	4.4504
48	100	Unbiased-100krad	1.5149	5.8242	4.3093
49	100	Unbiased-100krad	1.4219	5.0951	3.6732
50	105	Biased-100krad	1.9613	5.0926	3.1313
51	105	Biased-100krad	1.4469	5.421	3.9741
52	105	Biased-100krad	1.4456	6.5757	5.1301
53	105	Biased-100krad	1.4843	6.4153	4.931
54	105	Biased-100krad	1.4225	5.4178	3.9953

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.3901	1.4269	1.4825	0.048966	1.8075	1.8657	1.9142	0.054016	0.4174	0.4388	0.4673	0.025696
30	1.4107	1.6525	2.4583	0.4522	2.1171	2.3862	3.1657	0.44004	0.7064	0.73368	0.7775	0.035152
35	1.4356	1.4607	1.4787	0.019064	2.1352	2.1791	2.24	0.042106	0.6783	0.7184	0.7613	0.031863
50	1.3944	1.4786	1.5667	0.069262	2.3331	2.5101	2.6464	0.11309	0.9093	1.0315	1.1078	0.076115
55	1.4025	1.5119	1.6217	0.077738	2.7519	2.8617	3.0184	0.13297	1.2307	1.3498	1.4842	0.098407
100	1.4219	1.5264	1.6442	0.090235	4.9216	5.4449	6.0377	0.47467	3.4579	3.9185	4.4504	0.43442
105	1.4225	1.5521	1.9613	0.22981	5.0926	5.7845	6.5757	0.66506	3.1313	4.2324	5.1301	0.81075

Device Test: 31.3 _PWRGD|VOL/PWRGD3/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW





Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

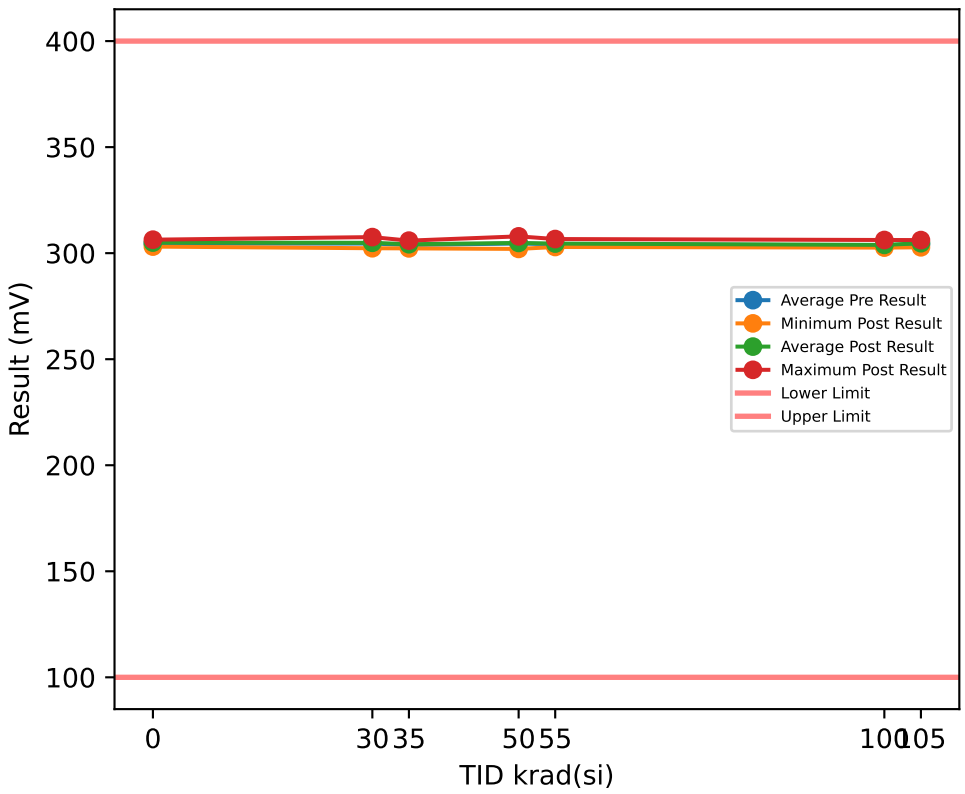
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	303.71	304.38	0.6639
2	0	CU2	301.27	301.92	0.6544
3	0	CU3	303.71	304.4	0.6888
11	30	Unbiased-30krad	301.33	301.92	0.5889
12	30	Unbiased-30krad	303.14	303.71	0.5732
13	30	Unbiased-30krad	301.09	301.72	0.6263
14	30	Unbiased-30krad	303.98	304.57	0.5951
15	30	Unbiased-30krad	305.66	306.36	0.695
16	35	Biased-30krad	304.35	304.97	0.6232
17	35	Biased-30krad	302.18	302.79	0.6045
18	35	Biased-30krad	303.48	304.01	0.5326
19	35	Biased-30krad	300.59	301.19	0.5983
20	35	Biased-30krad	301.44	301.85	0.4078
30	50	Unbiased-50krad	302.54	303.12	0.5764
31	50	Unbiased-50krad	300.93	301.56	0.6326
32	50	Unbiased-50krad	304.45	305.04	0.5889
33	50	Unbiased-50krad	303.39	303.86	0.4733
34	50	Unbiased-50krad	306.43	306.9	0.4764
40	55	Biased-50krad	301.03	301.52	0.489
41	55	Biased-50krad	301.9	302.57	0.6794
42	55	Biased-50krad	304.33	304.95	0.6201
43	55	Biased-50krad	304.21	304.72	0.5139
44	55	Biased-50krad	301.64	302.08	0.4359
45	100	Unbiased-100krad	301.55	302	0.4546
46	100	Unbiased-100krad	303.11	303.6	0.4827
47	100	Unbiased-100krad	301.04	301.48	0.4359
48	100	Unbiased-100krad	302.35	302.86	0.5077
49	100	Unbiased-100krad	304.69	305.24	0.5514
50	105	Biased-100krad	304.35	305.03	0.6794
51	105	Biased-100krad	301.75	302.39	0.642
52	105	Biased-100krad	303.44	304.18	0.7419
53	105	Biased-100krad	301.48	302.14	0.6607
54	105	Biased-100krad	305.09	305.72	0.6294

Test Statistics (mV)

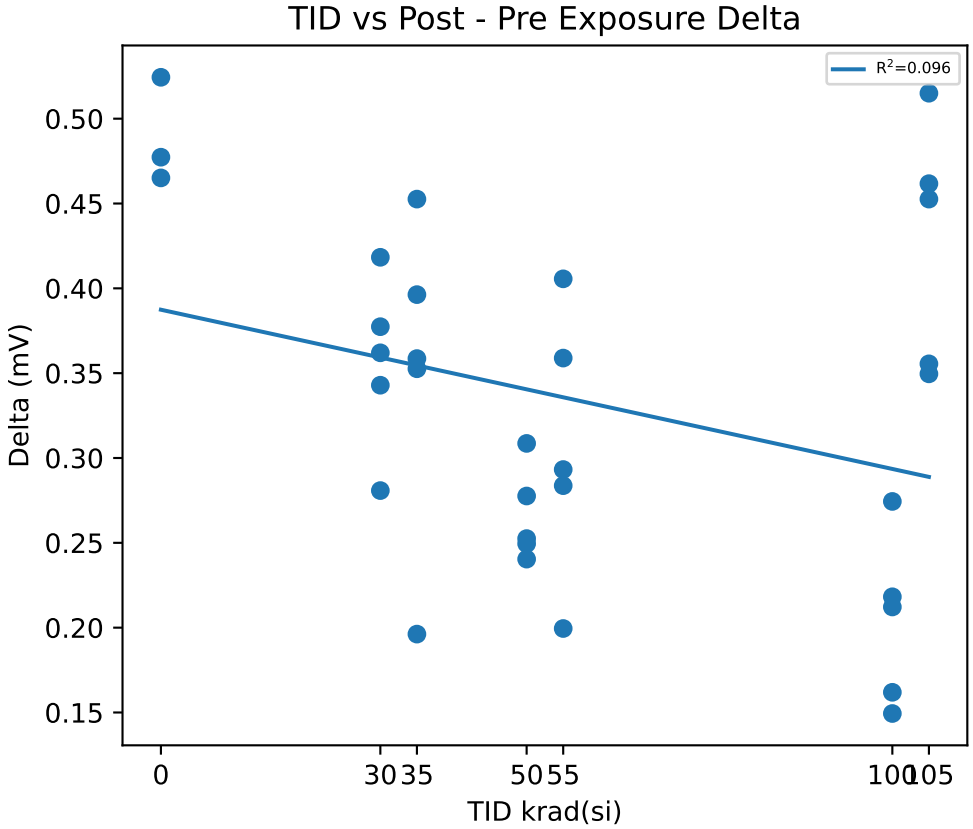
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	301.27	302.9	303.71	1.41	301.92	303.56	304.4	1.4227	0.6544	0.66903	0.6888	0.017765
30	301.09	303.04	305.66	1.9039	301.72	303.65	306.36	1.9319	0.5732	0.6157	0.695	0.048347
35	300.59	302.41	304.35	1.5151	301.19	302.96	304.97	1.544	0.4078	0.55328	0.6232	0.08822
50	300.93	303.55	306.43	2.0621	301.56	304.09	306.9	2.0133	0.4733	0.54952	0.6326	0.071295
55	301.03	302.62	304.33	1.536	301.52	303.17	304.95	1.5678	0.4359	0.54766	0.6794	0.099592
100	301.04	302.55	304.69	1.4322	301.48	303.03	305.24	1.4744	0.4359	0.48646	0.5514	0.045425
105	301.48	303.22	305.09	1.5824	302.14	303.89	305.72	1.5842	0.6294	0.67068	0.7419	0.044087

Device Test: 31.4 _PWRGD|VOL/PWRGD4/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW

TID vs Result Stats



TID vs Post - Pre Exposure Delta



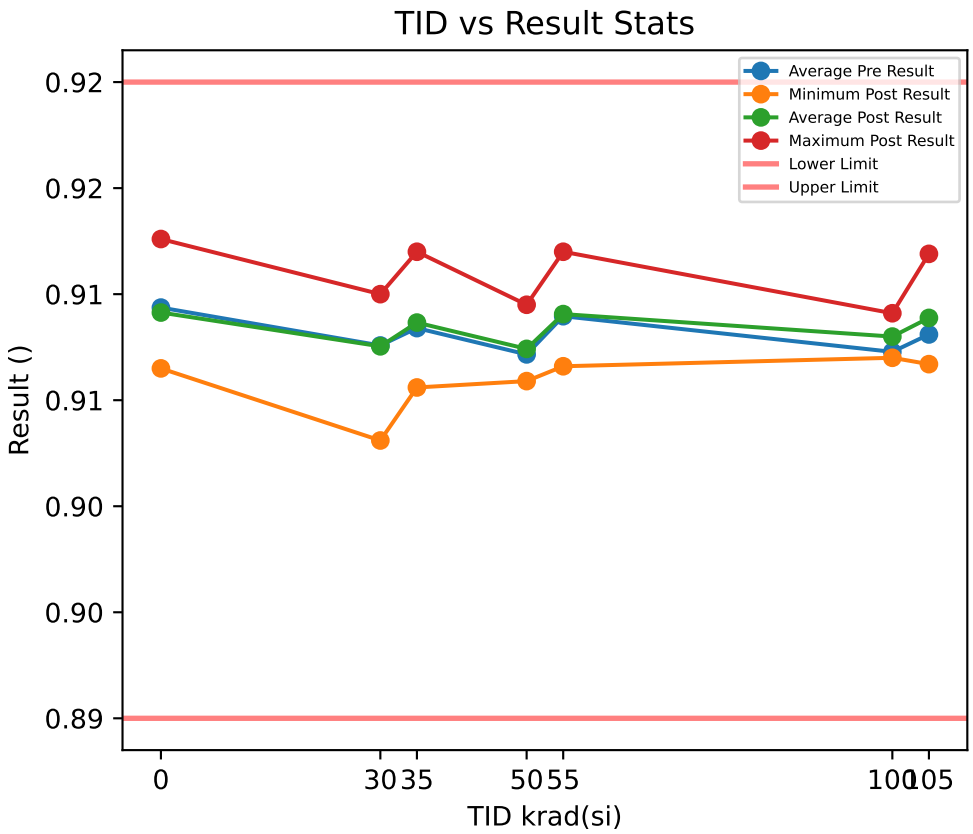
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (mV))

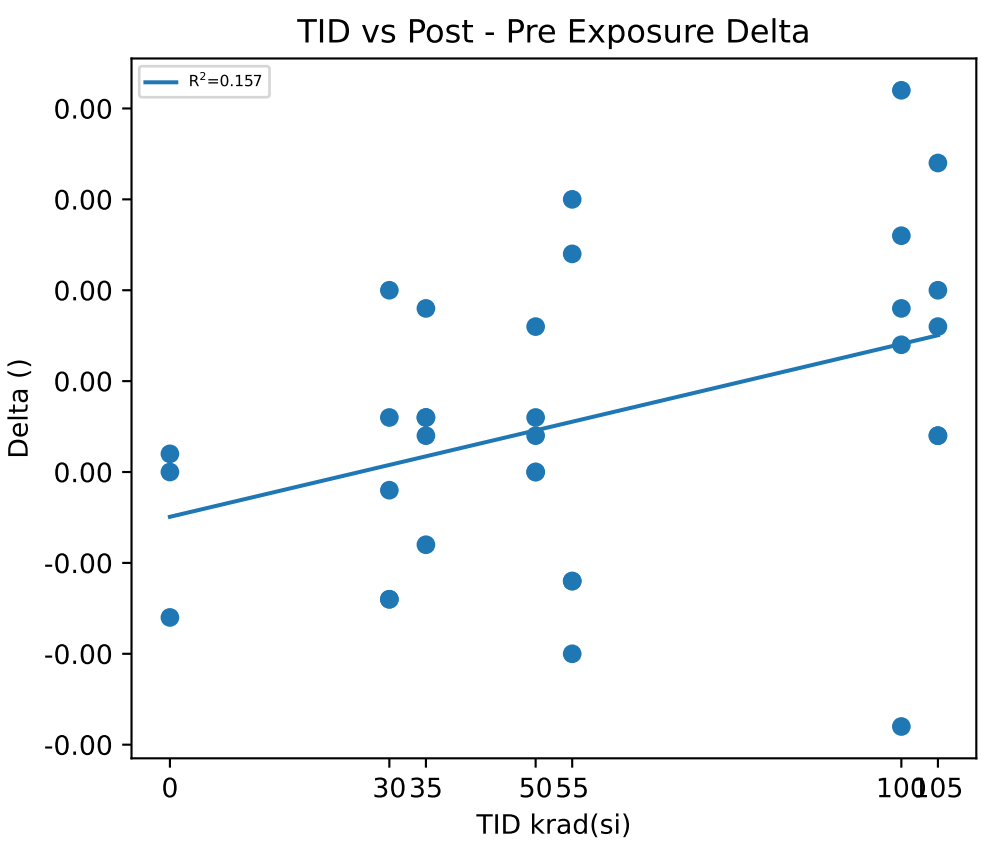
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	305.84	306.36	0.5244
2	0	CU2	302.62	303.09	0.4773
3	0	CU3	305.03	305.5	0.4651
11	30	Unbiased-30krad	303.3	303.68	0.3774
12	30	Unbiased-30krad	305.07	305.36	0.2808
13	30	Unbiased-30krad	301.98	302.32	0.3429
14	30	Unbiased-30krad	305.17	305.53	0.362
15	30	Unbiased-30krad	307.16	307.58	0.4183
16	35	Biased-30krad	305.46	305.91	0.4526
17	35	Biased-30krad	304.27	304.67	0.3963
18	35	Biased-30krad	305.33	305.68	0.3526
19	35	Biased-30krad	301.9	302.26	0.3586
20	35	Biased-30krad	302.34	302.53	0.1962
30	50	Unbiased-50krad	304.22	304.49	0.2776
31	50	Unbiased-50krad	301.69	302	0.3086
32	50	Unbiased-50krad	305.09	305.34	0.2495
33	50	Unbiased-50krad	304.1	304.35	0.2525
34	50	Unbiased-50krad	307.68	307.92	0.2404
40	55	Biased-50krad	302.63	302.91	0.2837
41	55	Biased-50krad	303.79	304.2	0.4056
42	55	Biased-50krad	306.3	306.66	0.3589
43	55	Biased-50krad	305	305.29	0.2932
44	55	Biased-50krad	303.36	303.56	0.1995
45	100	Unbiased-100krad	302.51	302.68	0.1619
46	100	Unbiased-100krad	304.13	304.4	0.2744
47	100	Unbiased-100krad	302.47	302.62	0.1494
48	100	Unbiased-100krad	303.36	303.57	0.2182
49	100	Unbiased-100krad	306	306.21	0.2122
50	105	Biased-100krad	305.54	305.99	0.4526
51	105	Biased-100krad	302.96	303.31	0.3555
52	105	Biased-100krad	304.72	305.24	0.515
53	105	Biased-100krad	302.3	302.76	0.4617
54	105	Biased-100krad	305.82	306.17	0.3496

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	302.62	304.49	305.84	1.6755	303.09	304.98	306.36	1.6926	0.4651	0.48893	0.5244	0.031315
30	301.98	304.53	307.16	1.9771	302.32	304.89	307.58	1.9945	0.2808	0.35628	0.4183	0.050501
35	301.9	303.86	305.46	1.6613	302.26	304.21	305.91	1.7237	0.1962	0.35126	0.4526	0.095391
50	301.69	304.56	307.68	2.1557	302	304.82	307.92	2.1316	0.2404	0.26572	0.3086	0.027653
55	302.63	304.22	306.3	1.4492	302.91	304.52	306.66	1.4828	0.1995	0.30818	0.4056	0.078578
100	302.47	303.69	306	1.4583	302.62	303.9	306.21	1.4865	0.1494	0.20322	0.2744	0.049939
105	302.3	304.27	305.82	1.5675	302.76	304.69	306.17	1.5656	0.3496	0.42688	0.515	0.071949

Device Test: 31.5 _PWRGD|FallingFault/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





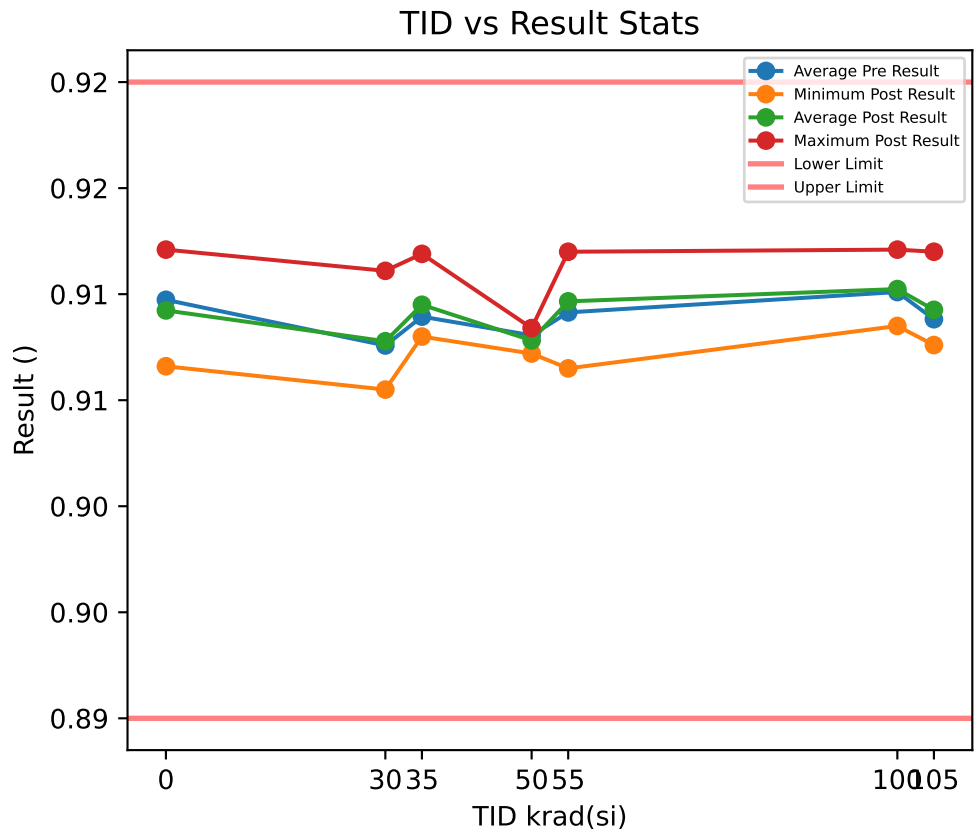
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

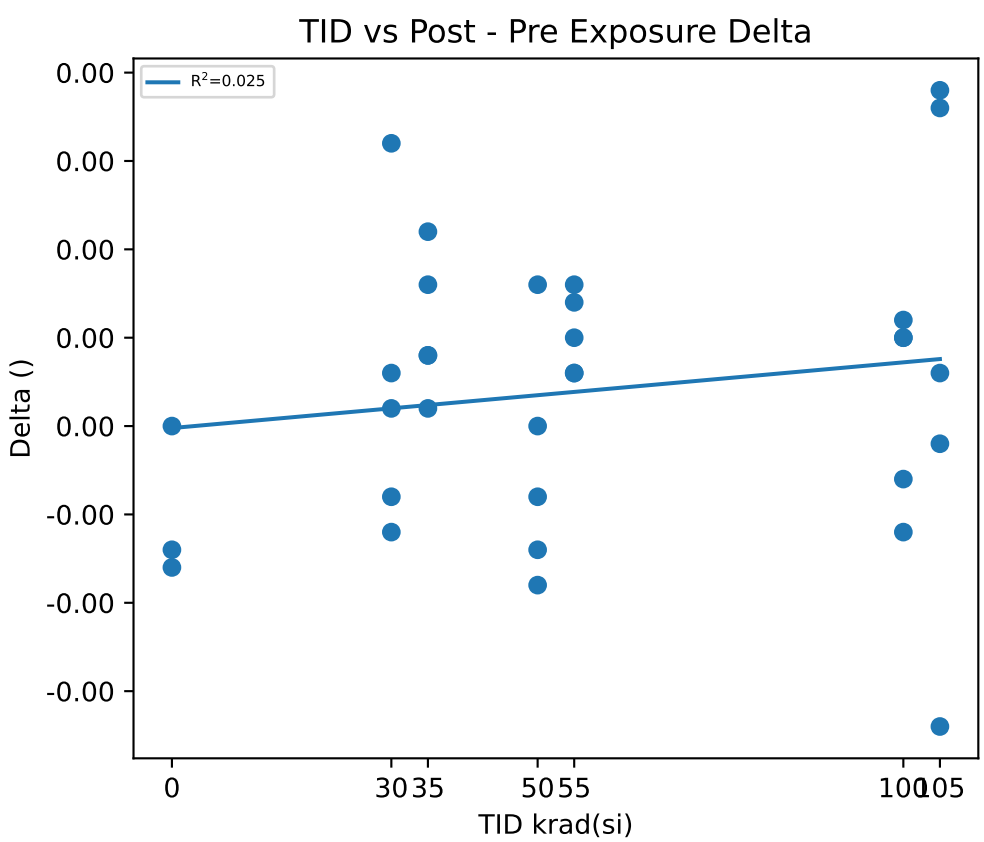
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9064	0.9065	0.0001
2	0	CU2	0.9134	0.9126	-0.0008
3	0	CU3	0.9083	0.9083	0
11	30	Unbiased-30krad	0.9085	0.9088	0.0003
12	30	Unbiased-30krad	0.909	0.91	0.001
13	30	Unbiased-30krad	0.9038	0.9031	-0.0007
14	30	Unbiased-30krad	0.9099	0.9092	-0.0007
15	30	Unbiased-30krad	0.9067	0.9066	-0.0001
16	35	Biased-30krad	0.9086	0.9095	0.0009
17	35	Biased-30krad	0.9076	0.9078	0.0002
18	35	Biased-30krad	0.9124	0.912	-0.0004
19	35	Biased-30krad	0.9053	0.9056	0.0003
20	35	Biased-30krad	0.9081	0.9084	0.0003
30	50	Unbiased-50krad	0.907	0.907	0
31	50	Unbiased-50krad	0.907	0.907	0
32	50	Unbiased-50krad	0.9069	0.9077	0.0008
33	50	Unbiased-50krad	0.9056	0.9059	0.0003
34	50	Unbiased-50krad	0.9093	0.9095	0.0002
40	55	Biased-50krad	0.9081	0.9075	-0.0006
41	55	Biased-50krad	0.9126	0.912	-0.0006
42	55	Biased-50krad	0.91	0.909	-0.001
43	55	Biased-50krad	0.909	0.9102	0.0012
44	55	Biased-50krad	0.9051	0.9066	0.0015
45	100	Unbiased-100krad	0.9064	0.9073	0.0009
46	100	Unbiased-100krad	0.9057	0.907	0.0013
47	100	Unbiased-100krad	0.907	0.9091	0.0021
48	100	Unbiased-100krad	0.9084	0.9091	0.0007
49	100	Unbiased-100krad	0.9089	0.9075	-0.0014
50	105	Biased-100krad	0.9071	0.9079	0.0008
51	105	Biased-100krad	0.9092	0.9094	0.0002
52	105	Biased-100krad	0.9065	0.9067	0.0002
53	105	Biased-100krad	0.9102	0.9119	0.0017
54	105	Biased-100krad	0.9075	0.9085	0.001

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9064	0.90937	0.9134	0.0036199	0.9065	0.90913	0.9126	0.0031342	-0.0008	-0.00023333	0.0001	0.00049329
30	0.9038	0.90758	0.9099	0.0024139	0.9031	0.90754	0.91	0.0027835	-0.0007	-4e-05	0.001	0.00071972
35	0.9053	0.9084	0.9124	0.0025681	0.9056	0.90866	0.912	0.0023469	-0.0004	0.00026	0.0009	0.00046152
50	0.9056	0.90716	0.9093	0.0013353	0.9059	0.90742	0.9095	0.0013293	0	0.00026	0.0008	0.00032863
55	0.9051	0.90896	0.9126	0.0027373	0.9066	0.90906	0.912	0.0021466	-0.001	0.0001	0.0015	0.0011576
100	0.9057	0.90728	0.9089	0.0013442	0.907	0.908	0.9091	0.0010198	-0.0014	0.00072	0.0021	0.0013008
105	0.9065	0.9081	0.9102	0.0015443	0.9067	0.90888	0.9119	0.0019524	0.0002	0.00078	0.0017	0.0006261

Device Test: 31.6 _PWRGD|FallingFault/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





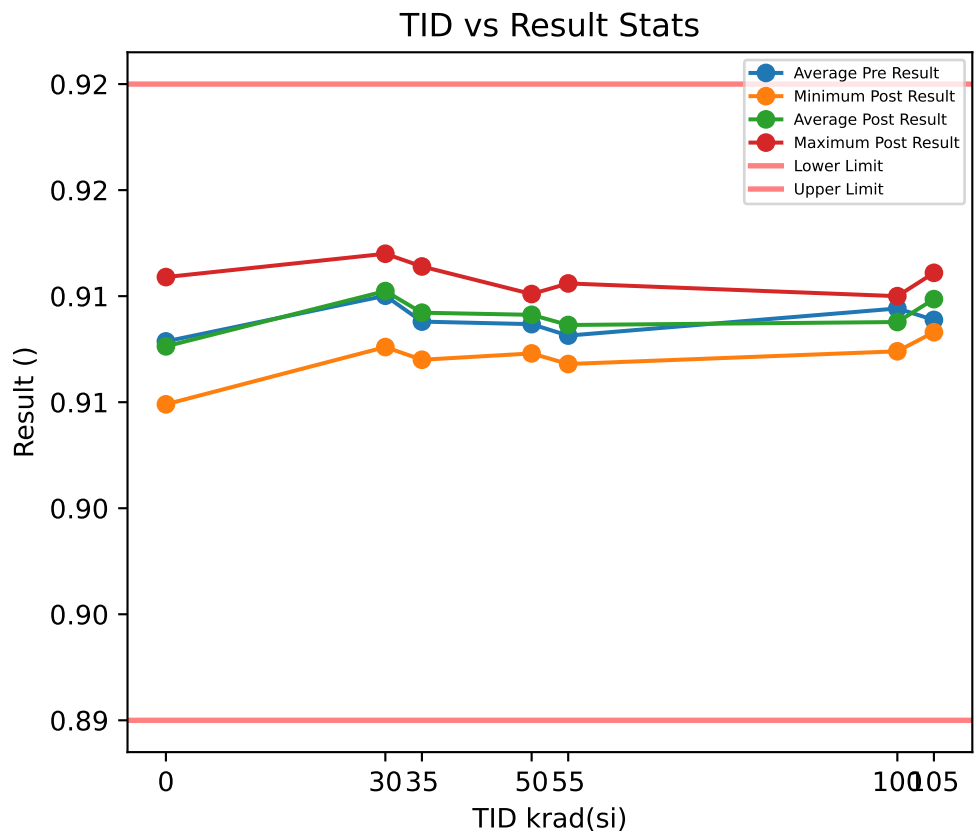
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

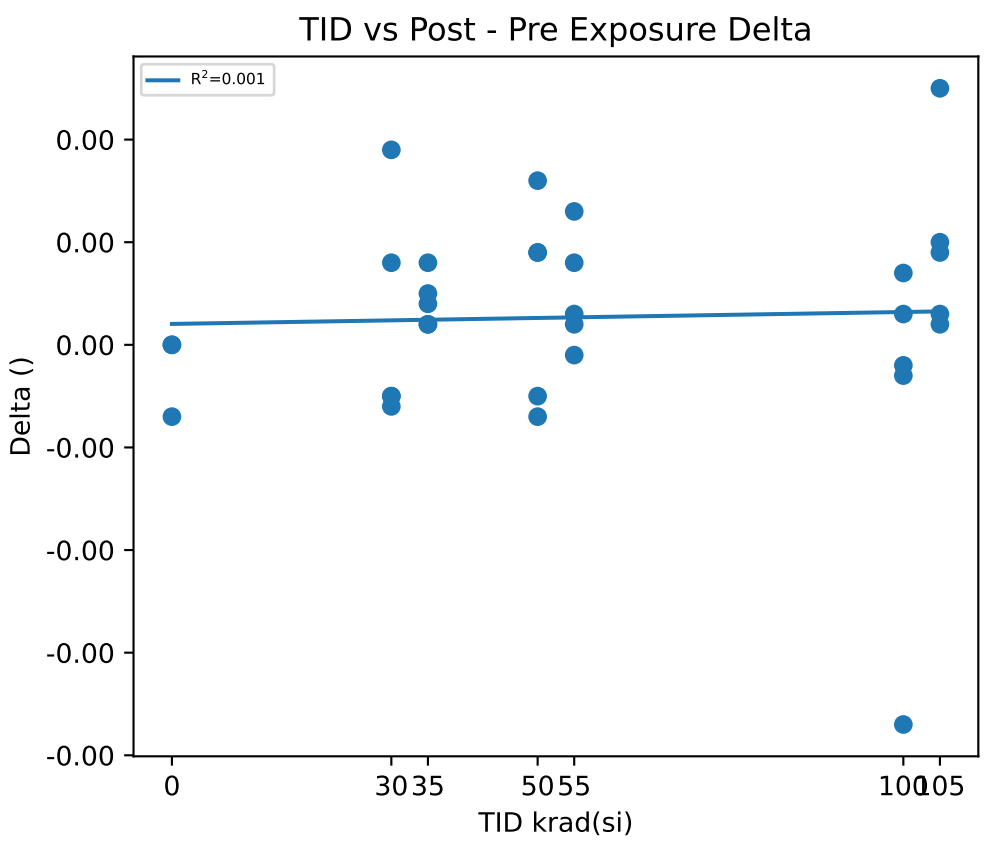
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9129	0.9121	-0.0008
2	0	CU2	0.9097	0.909	-0.0007
3	0	CU3	0.9066	0.9066	0
11	30	Unbiased-30krad	0.9059	0.9055	-0.0004
12	30	Unbiased-30krad	0.9088	0.9082	-0.0006
13	30	Unbiased-30krad	0.9108	0.9111	0.0003
14	30	Unbiased-30krad	0.9061	0.9062	0.0001
15	30	Unbiased-30krad	0.9063	0.9079	0.0016
16	35	Biased-30krad	0.9085	0.9093	0.0008
17	35	Biased-30krad	0.9079	0.908	0.0001
18	35	Biased-30krad	0.9076	0.908	0.0004
19	35	Biased-30krad	0.9115	0.9119	0.0004
20	35	Biased-30krad	0.9092	0.9103	0.0011
30	50	Unbiased-50krad	0.9072	0.9072	0
31	50	Unbiased-50krad	0.9083	0.9074	-0.0009
32	50	Unbiased-50krad	0.9076	0.9084	0.0008
33	50	Unbiased-50krad	0.9082	0.9078	-0.0004
34	50	Unbiased-50krad	0.909	0.9083	-0.0007
40	55	Biased-50krad	0.9115	0.912	0.0005
41	55	Biased-50krad	0.9104	0.9107	0.0003
42	55	Biased-50krad	0.9057	0.9065	0.0008
43	55	Biased-50krad	0.9089	0.9092	0.0003
44	55	Biased-50krad	0.9092	0.9099	0.0007
45	100	Unbiased-100krad	0.9127	0.9121	-0.0006
46	100	Unbiased-100krad	0.9079	0.9085	0.0006
47	100	Unbiased-100krad	0.9092	0.9097	0.0005
48	100	Unbiased-100krad	0.9109	0.9106	-0.0003
49	100	Unbiased-100krad	0.9098	0.9103	0.0005
50	105	Biased-100krad	0.9078	0.9077	-0.0001
51	105	Biased-100krad	0.9074	0.9092	0.0018
52	105	Biased-100krad	0.9079	0.9098	0.0019
53	105	Biased-100krad	0.9093	0.9076	-0.0017
54	105	Biased-100krad	0.9117	0.912	0.0003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9066	0.90973	0.9129	0.0031501	0.9066	0.90923	0.9121	0.0027574	-0.0008	-0.0005	0	0.00043589
30	0.9059	0.90758	0.9108	0.002151	0.9055	0.90778	0.9111	0.0021742	-0.0006	0.0002	0.0016	0.00086313
35	0.9076	0.90894	0.9115	0.0015566	0.908	0.9095	0.9119	0.0016538	0.0001	0.00056	0.0011	0.00039115
50	0.9072	0.90806	0.909	0.00069138	0.9072	0.90782	0.9084	0.00053104	-0.0009	-0.00024	0.0008	0.00067305
55	0.9057	0.90914	0.9115	0.0021824	0.9065	0.90966	0.912	0.0020501	0.0003	0.00052	0.0008	0.00022804
100	0.9079	0.9101	0.9127	0.0018125	0.9085	0.91024	0.9121	0.0013145	-0.0006	0.00014	0.0006	0.00055045
105	0.9074	0.90882	0.9117	0.0017627	0.9076	0.90926	0.912	0.0018022	-0.0017	0.00044	0.0019	0.0014893

Device Test: 31.7 _PWRGD|FallingFault/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





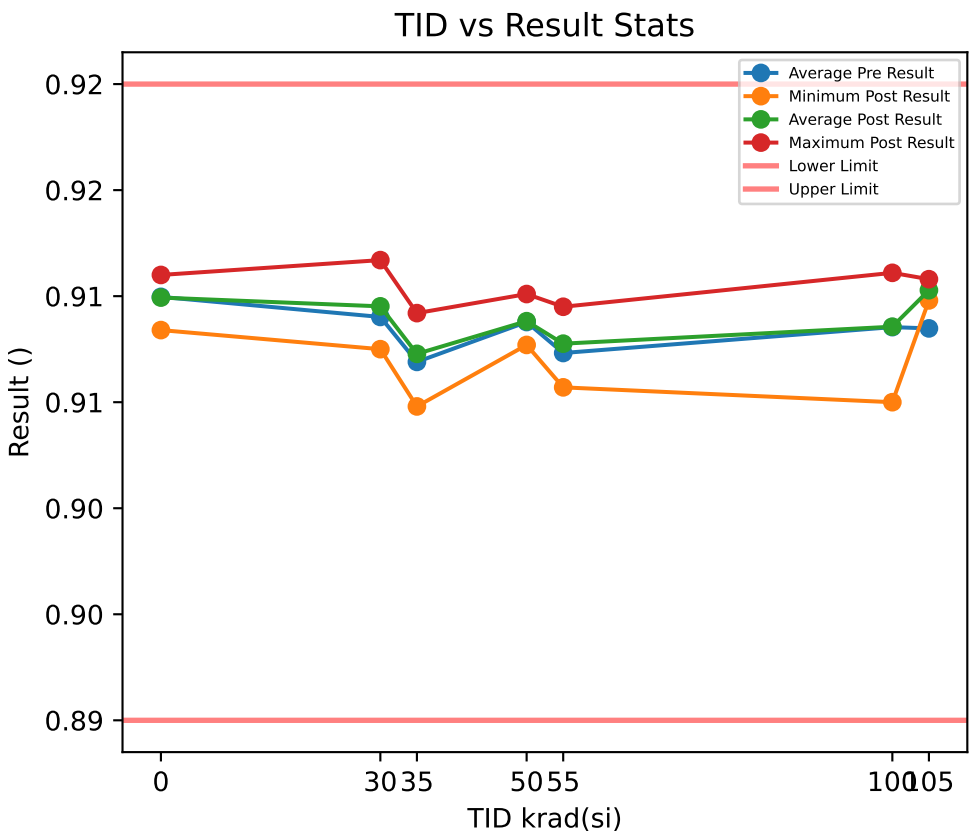
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

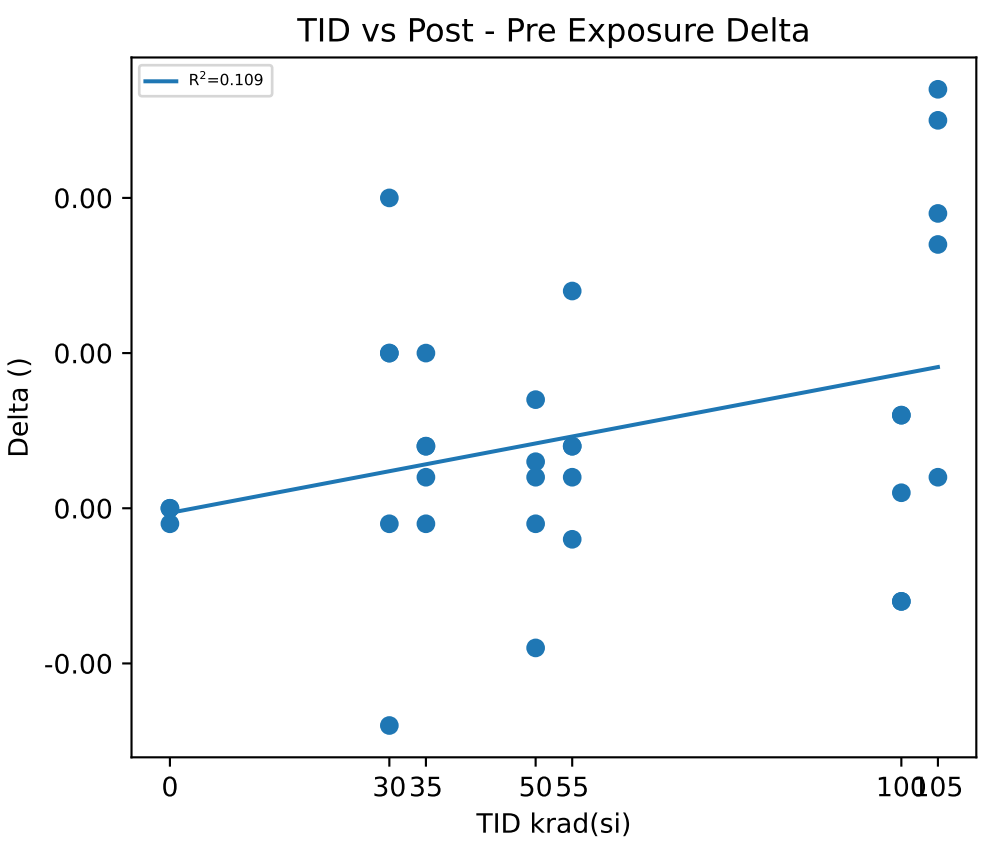
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9116	0.9109	-0.0007
2	0	CU2	0.9049	0.9049	0
3	0	CU3	0.9071	0.9071	0
11	30	Unbiased-30krad	0.9116	0.9111	-0.0005
12	30	Unbiased-30krad	0.9101	0.912	0.0019
13	30	Unbiased-30krad	0.9123	0.9118	-0.0005
14	30	Unbiased-30krad	0.9082	0.9076	-0.0006
15	30	Unbiased-30krad	0.9079	0.9087	0.0008
16	35	Biased-30krad	0.9093	0.9101	0.0008
17	35	Biased-30krad	0.9087	0.9089	0.0002
18	35	Biased-30krad	0.9083	0.9087	0.0004
19	35	Biased-30krad	0.9109	0.9114	0.0005
20	35	Biased-30krad	0.9068	0.907	0.0002
30	50	Unbiased-50krad	0.9064	0.9073	0.0009
31	50	Unbiased-50krad	0.9073	0.9089	0.0016
32	50	Unbiased-50krad	0.9092	0.9101	0.0009
33	50	Unbiased-50krad	0.9102	0.9097	-0.0005
34	50	Unbiased-50krad	0.9103	0.9096	-0.0007
40	55	Biased-50krad	0.9087	0.9089	0.0002
41	55	Biased-50krad	0.9086	0.9089	0.0003
42	55	Biased-50krad	0.9098	0.9106	0.0008
43	55	Biased-50krad	0.9067	0.908	0.0013
44	55	Biased-50krad	0.9069	0.9068	-0.0001
45	100	Unbiased-100krad	0.9071	0.9078	0.0007
46	100	Unbiased-100krad	0.9096	0.9093	-0.0003
47	100	Unbiased-100krad	0.9071	0.9074	0.0003
48	100	Unbiased-100krad	0.9102	0.91	-0.0002
49	100	Unbiased-100krad	0.9131	0.9094	-0.0037
50	105	Biased-100krad	0.9076	0.9101	0.0025
51	105	Biased-100krad	0.9109	0.9111	0.0002
52	105	Biased-100krad	0.9087	0.9097	0.001
53	105	Biased-100krad	0.9074	0.9083	0.0009
54	105	Biased-100krad	0.9098	0.9101	0.0003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9049	0.90787	0.9116	0.0034152	0.9049	0.90763	0.9109	0.0030353	-0.0007	-0.00023333	0	0.00040415
30	0.9079	0.91002	0.9123	0.001969	0.9076	0.91024	0.912	0.0019756	-0.0006	0.00022	0.0019	0.0011032
35	0.9068	0.9088	0.9109	0.0014933	0.907	0.90922	0.9114	0.0016453	0.0002	0.00042	0.0008	0.000249
50	0.9064	0.90868	0.9103	0.0017541	0.9073	0.90912	0.9101	0.0011054	-0.0007	0.00044	0.0016	0.00099398
55	0.9067	0.90814	0.9098	0.0013126	0.9068	0.90864	0.9106	0.0013939	-0.0001	0.0005	0.0013	0.00055227
100	0.9071	0.90942	0.9131	0.0024974	0.9074	0.90878	0.91	0.0011189	-0.0037	-0.00064	0.0007	0.0017573
105	0.9074	0.90888	0.9109	0.0014822	0.9083	0.90986	0.9111	0.0010139	0.0002	0.00098	0.0025	0.00092033

Device Test: 31.8 _PWRGD|FallingFault/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING_FAULT





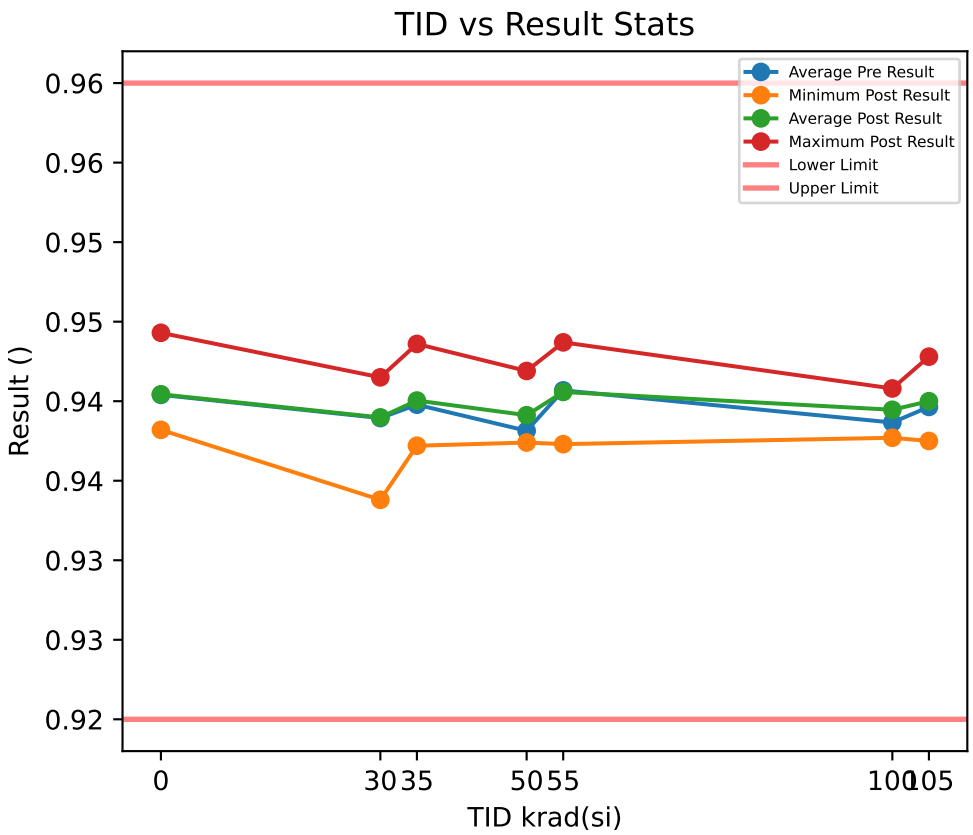
Test Results (Lower Limit = 0.89, Upper Limit = 0.92 ())

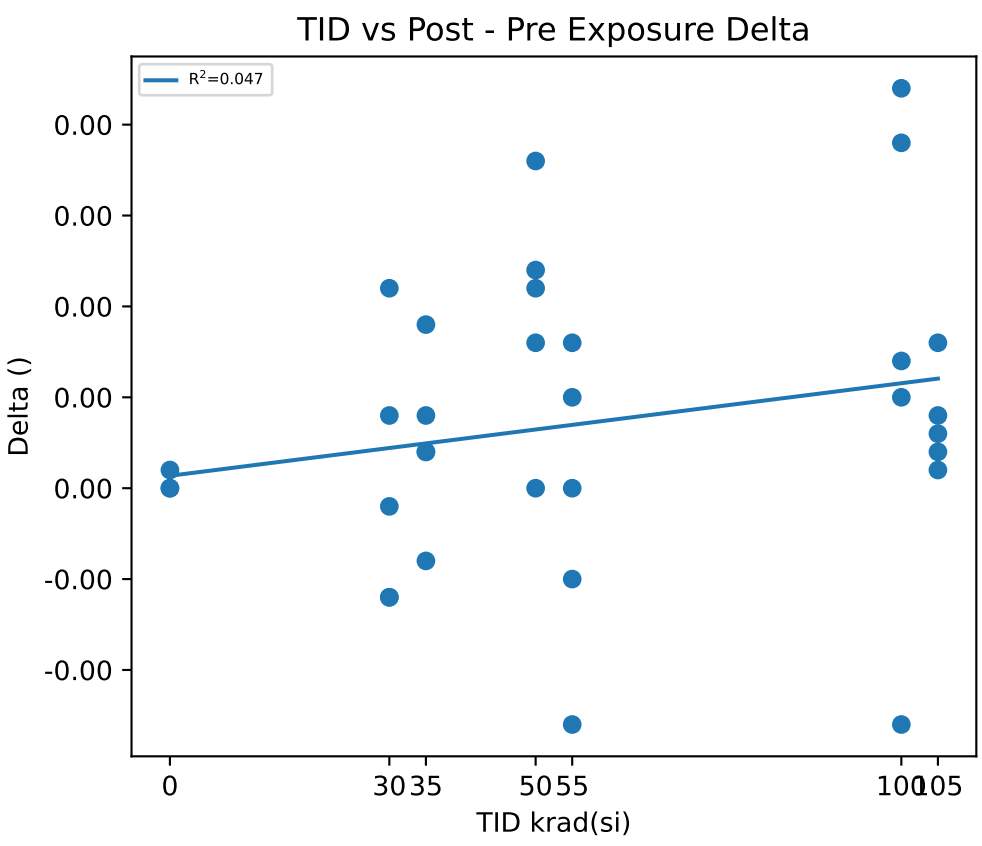
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.911	0.911	0
2	0	CU2	0.9084	0.9084	0
3	0	CU3	0.9105	0.9104	-0.0001
11	30	Unbiased-30krad	0.9095	0.9081	-0.0014
12	30	Unbiased-30krad	0.9065	0.9075	0.001
13	30	Unbiased-30krad	0.9076	0.9096	0.002
14	30	Unbiased-30krad	0.9107	0.9117	0.001
15	30	Unbiased-30krad	0.9108	0.9107	-0.0001
16	35	Biased-30krad	0.9049	0.9048	-0.0001
17	35	Biased-30krad	0.9068	0.907	0.0002
18	35	Biased-30krad	0.9073	0.9077	0.0004
19	35	Biased-30krad	0.9088	0.9092	0.0004
20	35	Biased-30krad	0.9067	0.9077	0.001
30	50	Unbiased-50krad	0.9084	0.9083	-0.0001
31	50	Unbiased-50krad	0.907	0.9077	0.0007
32	50	Unbiased-50krad	0.91	0.9091	-0.0009
33	50	Unbiased-50krad	0.9086	0.9089	0.0003
34	50	Unbiased-50krad	0.9099	0.9101	0.0002
40	55	Biased-50krad	0.9088	0.909	0.0002
41	55	Biased-50krad	0.9091	0.9095	0.0004
42	55	Biased-50krad	0.9063	0.9077	0.0014
43	55	Biased-50krad	0.9065	0.9069	0.0004
44	55	Biased-50krad	0.9059	0.9057	-0.0002
45	100	Unbiased-100krad	0.911	0.9111	0.0001
46	100	Unbiased-100krad	0.9105	0.9111	0.0006
47	100	Unbiased-100krad	0.9087	0.9081	-0.0006
48	100	Unbiased-100krad	0.9044	0.905	0.0006
49	100	Unbiased-100krad	0.9081	0.9075	-0.0006
50	105	Biased-100krad	0.9075	0.91	0.0025
51	105	Biased-100krad	0.9096	0.9098	0.0002
52	105	Biased-100krad	0.9082	0.9101	0.0019
53	105	Biased-100krad	0.9091	0.9108	0.0017
54	105	Biased-100krad	0.908	0.9107	0.0027

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9084	0.90997	0.911	0.0013796	0.9084	0.90993	0.911	0.0013614	-0.0001	-3.3333e-05	0	5.7735e-05
30	0.9065	0.90902	0.9108	0.0019097	0.9075	0.90952	0.9117	0.0017499	-0.0014	0.0005	0.002	0.0012961
35	0.9049	0.9069	0.9088	0.0013982	0.9048	0.90728	0.9092	0.0016022	-0.0001	0.00038	0.001	0.00040249
50	0.907	0.90878	0.91	0.0012337	0.9077	0.90882	0.9101	0.00090111	-0.0009	4e-05	0.0007	0.00059833
55	0.9059	0.90732	0.9091	0.0015073	0.9057	0.90776	0.9095	0.0015453	-0.0002	0.00044	0.0014	0.00058992
100	0.9044	0.90854	0.911	0.0026102	0.905	0.90856	0.9111	0.0025938	-0.0006	2e-05	0.0006	0.00060166
105	0.9075	0.90848	0.9096	0.00085264	0.9098	0.91028	0.9108	0.00044385	0.0002	0.0018	0.0027	0.00098489

Device Test: 31.9 _PWRGD|RisingGood/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_GOOD





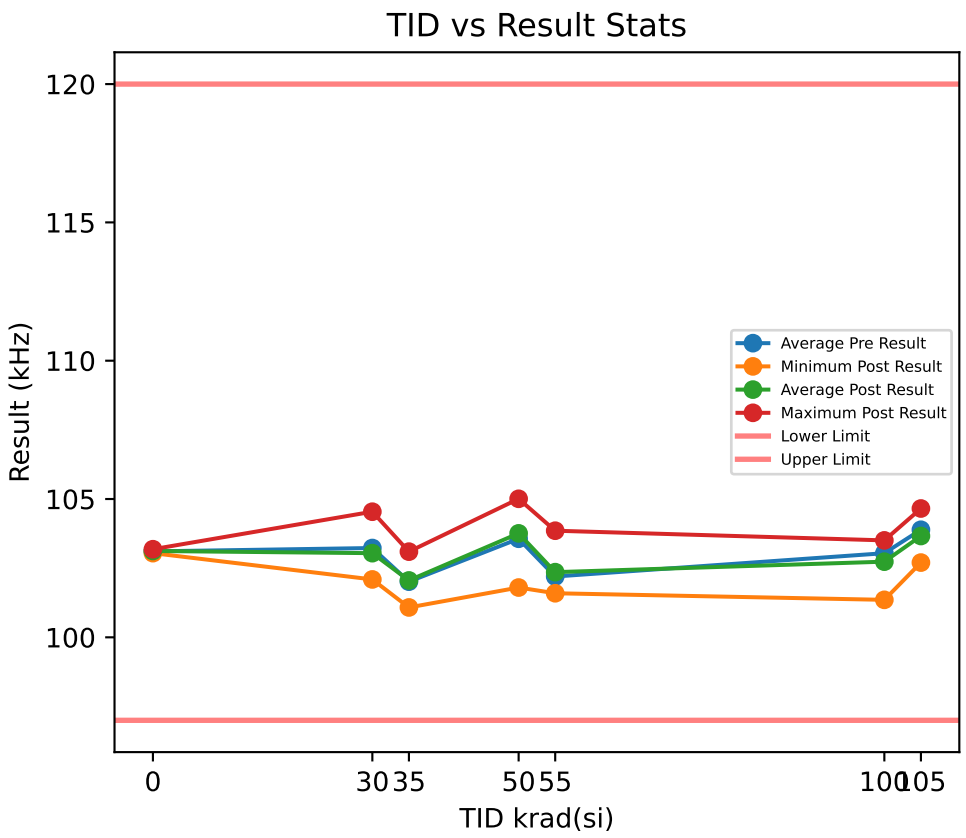
Test Results (Lower Limit = 0.92, Upper Limit = 0.96 ())

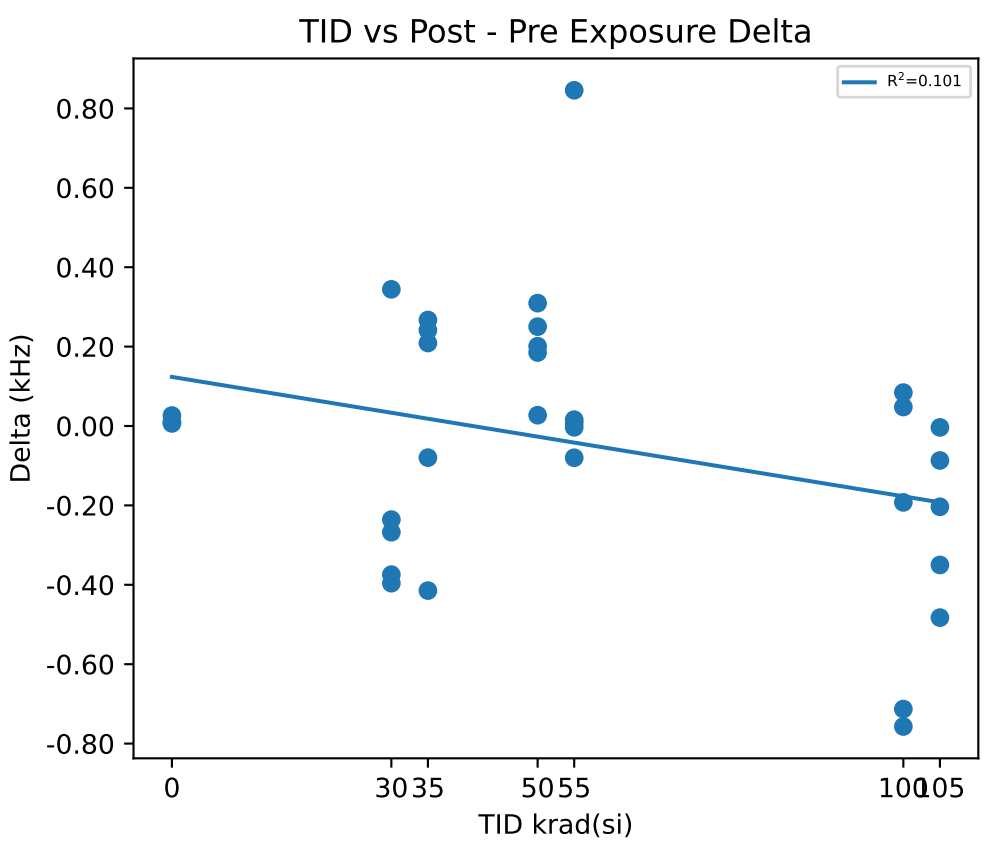
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.9388	0.9388	0
2	0	CU2	0.9442	0.9443	0.0001
3	0	CU3	0.9382	0.9382	0
11	30	Unbiased-30krad	0.941	0.9414	0.0004
12	30	Unbiased-30krad	0.9404	0.9415	0.0011
13	30	Unbiased-30krad	0.9344	0.9338	-0.0006
14	30	Unbiased-30krad	0.9415	0.9409	-0.0006
15	30	Unbiased-30krad	0.9374	0.9373	-0.0001
16	35	Biased-30krad	0.9393	0.9402	0.0009
17	35	Biased-30krad	0.9391	0.9393	0.0002
18	35	Biased-30krad	0.944	0.9436	-0.0004
19	35	Biased-30krad	0.9368	0.9372	0.0004
20	35	Biased-30krad	0.9397	0.9399	0.0002
30	50	Unbiased-50krad	0.9377	0.9385	0.0008
31	50	Unbiased-50krad	0.9377	0.9377	0
32	50	Unbiased-50krad	0.9383	0.9401	0.0018
33	50	Unbiased-50krad	0.9362	0.9374	0.0012
34	50	Unbiased-50krad	0.9408	0.9419	0.0011
40	55	Biased-50krad	0.9397	0.9384	-0.0013
41	55	Biased-50krad	0.9442	0.9437	-0.0005
42	55	Biased-50krad	0.9416	0.9416	0
43	55	Biased-50krad	0.9414	0.9419	0.0005
44	55	Biased-50krad	0.9365	0.9373	0.0008
45	100	Unbiased-100krad	0.9379	0.9398	0.0019
46	100	Unbiased-100krad	0.9372	0.9377	0.0005
47	100	Unbiased-100krad	0.9385	0.9407	0.0022
48	100	Unbiased-100krad	0.9401	0.9408	0.0007
49	100	Unbiased-100krad	0.9396	0.9383	-0.0013
50	105	Biased-100krad	0.9387	0.9395	0.0008
51	105	Biased-100krad	0.9407	0.941	0.0003
52	105	Biased-100krad	0.9371	0.9375	0.0004
53	105	Biased-100krad	0.9427	0.9428	0.0001
54	105	Biased-100krad	0.939	0.9392	0.0002

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9382	0.9404	0.9442	0.0033045	0.9382	0.94043	0.9443	0.003362	0	3.3333e-05	0.0001	5.7735e-05
30	0.9344	0.93894	0.9415	0.0029963	0.9338	0.93898	0.9415	0.0033745	-0.0006	4e-05	0.0011	0.00072319
35	0.9368	0.93978	0.944	0.0026167	0.9372	0.94004	0.9436	0.0023093	-0.0004	0.00026	0.0009	0.0004669
50	0.9362	0.93814	0.9408	0.0016772	0.9374	0.93912	0.9419	0.001874	0	0.00098	0.0018	0.00065727
55	0.9365	0.94068	0.9442	0.0028367	0.9373	0.94058	0.9437	0.0026471	-0.0013	-0.0001	0.0008	0.00083367
100	0.9372	0.93866	0.9401	0.0011929	0.9377	0.93946	0.9408	0.0014046	-0.0013	0.0008	0.0022	0.0013856
105	0.9371	0.93964	0.9427	0.0021349	0.9375	0.94	0.9428	0.0019987	0.0001	0.00036	0.0008	0.00027019

Device Test: 32.2 _IntFreq|Freq/RT_511/3/3///90.9/634//1.8///@EXT_SET_FREQ_100KHZ





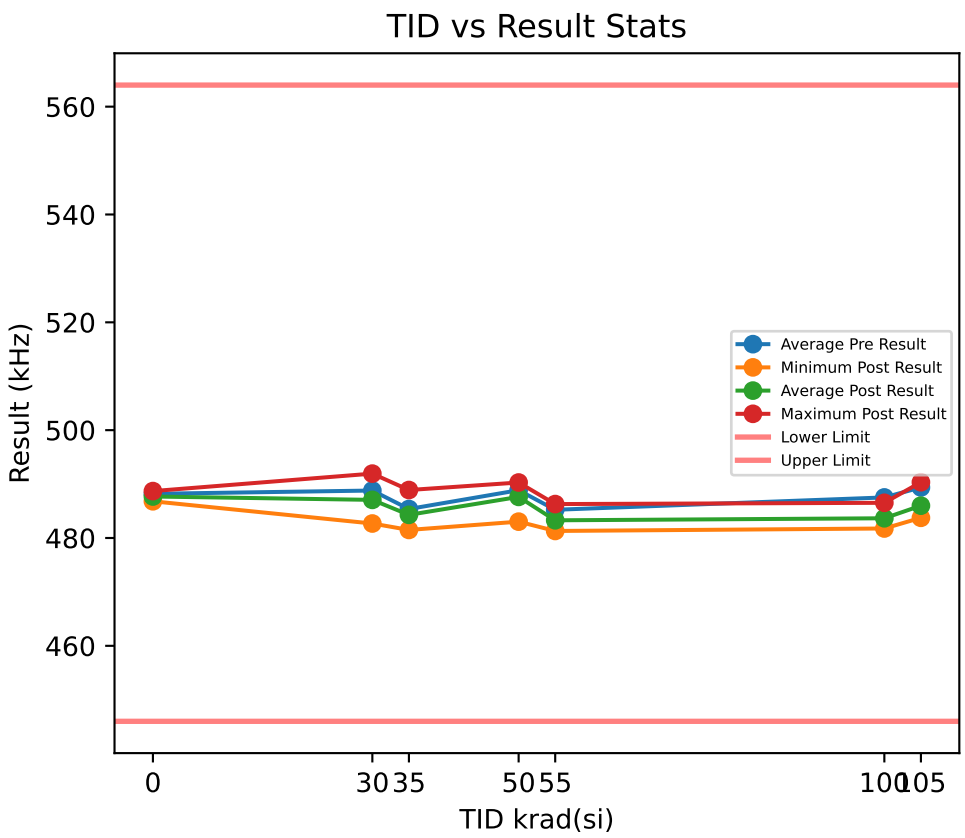
Test Results (Lower Limit = 97.0, Upper Limit = 120.0 (kHz))

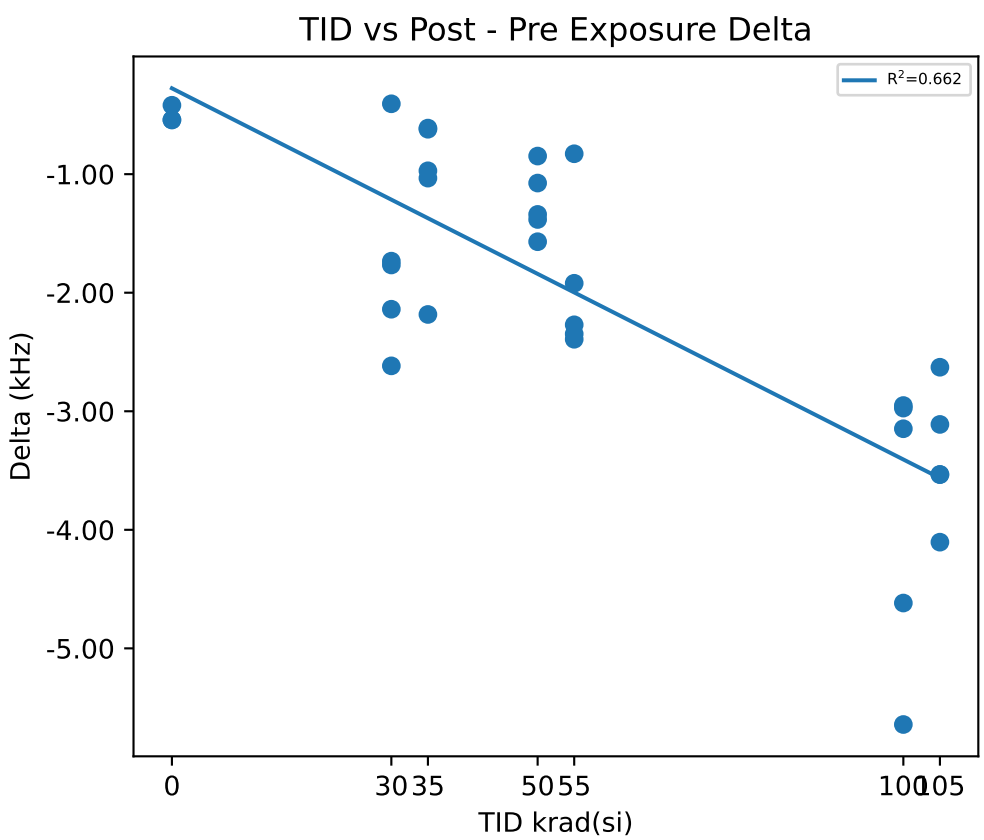
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.16	103.18	0.0264
2	0	CU2	103.03	103.04	0.0106
3	0	CU3	103.13	103.14	0.0065
11	30	Unbiased-30krad	102.36	102.13	-0.2358
12	30	Unbiased-30krad	102.49	102.09	-0.396
13	30	Unbiased-30krad	102.75	103.09	0.3443
14	30	Unbiased-30krad	103.63	103.36	-0.2676
15	30	Unbiased-30krad	104.92	104.54	-0.3744
16	35	Biased-30krad	102.61	102.88	0.267
17	35	Biased-30krad	100.84	101.08	0.2415
18	35	Biased-30krad	102.89	103.1	0.2091
19	35	Biased-30krad	102.4	101.99	-0.4146
20	35	Biased-30krad	101.32	101.24	-0.0797
30	50	Unbiased-50krad	103.56	103.59	0.0272
31	50	Unbiased-50krad	101.61	101.8	0.1851
32	50	Unbiased-50krad	103.75	104.06	0.3095
33	50	Unbiased-50krad	104.76	105.01	0.2503
34	50	Unbiased-50krad	104.14	104.34	0.201
40	55	Biased-50krad	101.6	101.59	-0.0034
41	55	Biased-50krad	103.01	103.85	0.8457
42	55	Biased-50krad	102.28	102.2	-0.08
43	55	Biased-50krad	102.26	102.26	0.0079
44	55	Biased-50krad	101.85	101.87	0.016
45	100	Unbiased-100krad	102.62	102.66	0.0478
46	100	Unbiased-100krad	103.7	103.5	-0.1924
47	100	Unbiased-100krad	102.11	101.36	-0.757
48	100	Unbiased-100krad	103.36	102.65	-0.713
49	100	Unbiased-100krad	103.42	103.5	0.0842
50	105	Biased-100krad	104.4	104.31	-0.0868
51	105	Biased-100krad	103.58	103.23	-0.35
52	105	Biased-100krad	105.14	104.66	-0.4827
53	105	Biased-100krad	102.91	102.7	-0.2035
54	105	Biased-100krad	103.41	103.41	-0.0035

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	103.03	103.11	103.16	0.066183	103.04	103.12	103.18	0.072166	0.0065	0.0145	0.0264	0.010508
30	102.36	103.23	104.92	1.0645	102.09	103.04	104.54	1.0107	-0.396	-0.1859	0.3443	0.30412
35	100.84	102.01	102.89	0.88455	101.08	102.06	103.1	0.9191	-0.4146	0.04466	0.267	0.29224
50	101.61	103.56	104.76	1.1816	101.8	103.76	105.01	1.2094	0.0272	0.19462	0.3095	0.10543
55	101.6	102.2	103.01	0.53534	101.59	102.36	103.85	0.87977	-0.08	0.15724	0.8457	0.38675
100	102.11	103.04	103.7	0.65556	101.36	102.74	103.5	0.88031	-0.757	-0.30608	0.0842	0.40601
105	102.91	103.89	105.14	0.88262	102.7	103.66	104.66	0.80418	-0.4827	-0.2253	-0.0035	0.19407

Device Test: 32.3 _IntFreq|Freq/RT_90P9/3/3///90.9/634//1.8///@EXT_SET_FREQ_500KHZ





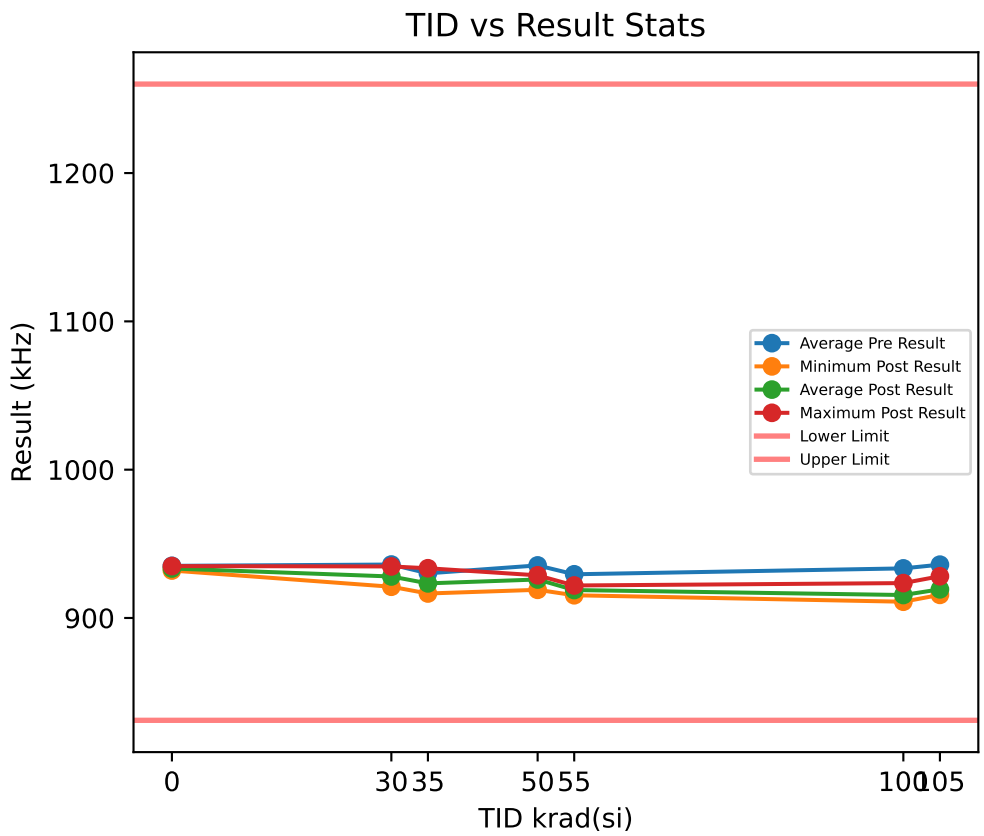
Test Results (Lower Limit = 446.0, Upper Limit = 564.0 (kHz))

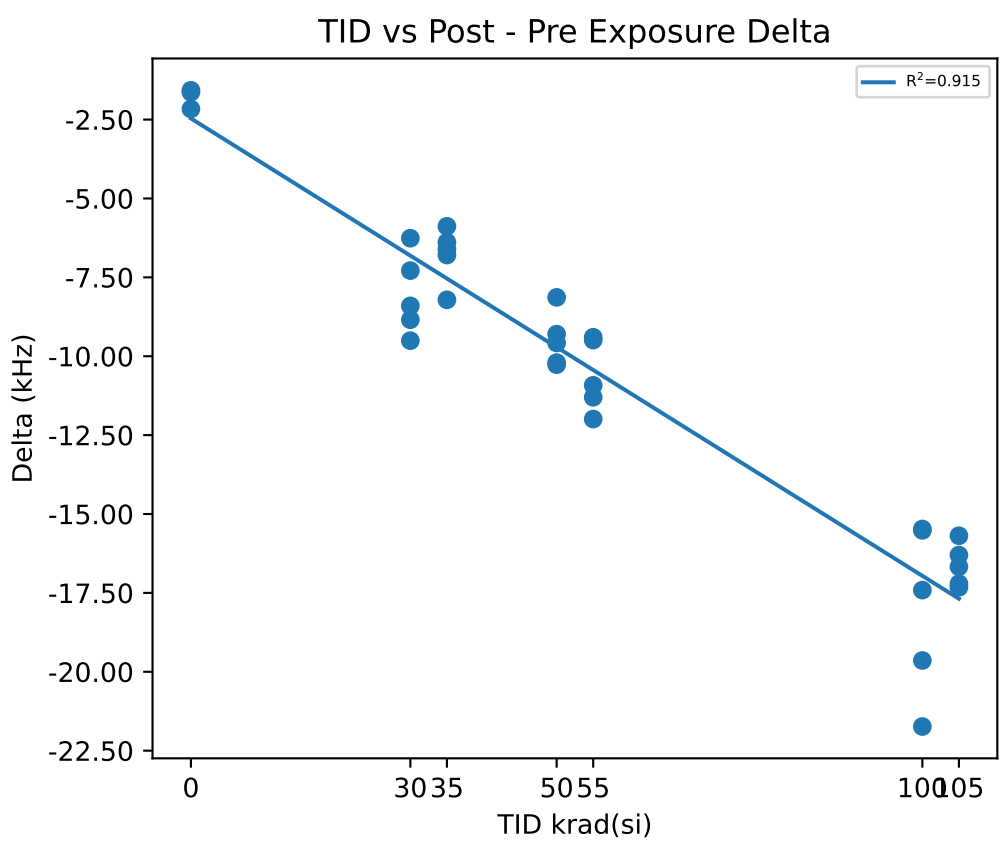
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	489.24	488.7	-0.5428
2	0	CU2	487.35	486.81	-0.5416
3	0	CU3	488	487.58	-0.4187
11	30	Unbiased-30krad	485.3	482.69	-2.617
12	30	Unbiased-30krad	489.09	487.33	-1.766
13	30	Unbiased-30krad	487.84	487.43	-0.4064
14	30	Unbiased-30krad	487.7	485.96	-1.7338
15	30	Unbiased-30krad	494.08	491.94	-2.1393
16	35	Biased-30krad	486.62	486	-0.6211
17	35	Biased-30krad	482.19	481.58	-0.6114
18	35	Biased-30krad	489.93	488.9	-1.0334
19	35	Biased-30krad	485.68	483.5	-2.1834
20	35	Biased-30krad	482.47	481.49	-0.9716
30	50	Unbiased-50krad	489.14	487.76	-1.3822
31	50	Unbiased-50krad	483.88	483.03	-0.8473
32	50	Unbiased-50krad	489.25	488.17	-1.075
33	50	Unbiased-50krad	491.86	490.29	-1.5698
34	50	Unbiased-50krad	490.2	488.86	-1.3395
40	55	Biased-50krad	484.02	482.1	-1.9204
41	55	Biased-50krad	487.12	486.29	-0.8279
42	55	Biased-50krad	486.75	484.48	-2.2707
43	55	Biased-50krad	484.62	482.22	-2.3927
44	55	Biased-50krad	483.65	481.3	-2.3475
45	100	Unbiased-100krad	484.71	481.76	-2.9516
46	100	Unbiased-100krad	489.67	486.53	-3.1475
47	100	Unbiased-100krad	486.41	481.79	-4.6176
48	100	Unbiased-100krad	488.32	482.68	-5.6423
49	100	Unbiased-100krad	488.5	485.53	-2.9733
50	105	Biased-100krad	489.85	486.74	-3.111
51	105	Biased-100krad	487.55	484.02	-3.5331
52	105	Biased-100krad	493.87	490.34	-3.5341
53	105	Biased-100krad	487.85	483.74	-4.1042
54	105	Biased-100krad	487.76	485.13	-2.6286

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	487.35	488.2	489.24	0.96225	486.81	487.69	488.7	0.95152	-0.5428	-0.50103	-0.4187	0.071305
30	485.3	488.8	494.08	3.253	482.69	487.07	491.94	3.33	-2.617	-1.7325	-0.4064	0.82272
35	482.19	485.38	489.93	3.202	481.49	484.29	488.9	3.1603	-2.1834	-1.0842	-0.6114	0.6445
50	483.88	488.86	491.86	2.9935	483.03	487.62	490.29	2.7412	-1.5698	-1.2428	-0.8473	0.28297
55	483.65	485.23	487.12	1.5974	481.3	483.28	486.29	2.0563	-2.3927	-1.9518	-0.8279	0.65513
100	484.71	487.52	489.67	1.9587	481.76	483.66	486.53	2.2223	-5.6423	-3.8665	-2.9516	1.2113
105	487.55	489.38	493.87	2.6803	483.74	486	490.34	2.6997	-4.1042	-3.3822	-2.6286	0.54968

Device Test: 32.4 _IntFreq|Freq/RT37P4/3/3///90.9/634//1.8///@EXT_SET_FREQ_1000KHZ





Test Results (Lower Limit = 831.0, Upper Limit = 1260.0 (kHz))

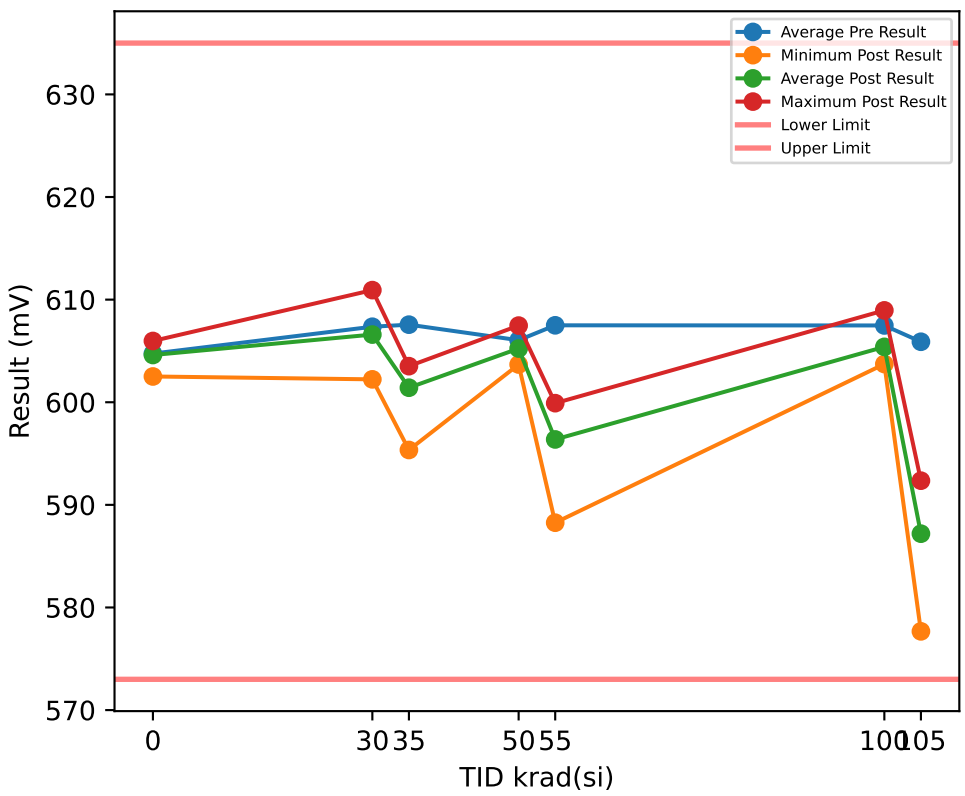
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	937.16	934.99	-2.1622
2	0	CU2	933.63	931.99	-1.6325
3	0	CU3	934.7	933.12	-1.572
11	30	Unbiased-30krad	929.9	921.06	-8.842
12	30	Unbiased-30krad	939.44	932.15	-7.286
13	30	Unbiased-30krad	933.72	927.46	-6.2602
14	30	Unbiased-30krad	932.88	924.47	-8.4037
15	30	Unbiased-30krad	944.25	934.74	-9.5062
16	35	Biased-30krad	932.17	926.29	-5.8822
17	35	Biased-30krad	923.82	917.43	-6.3871
18	35	Biased-30krad	940.13	933.53	-6.599
19	35	Biased-30krad	931.12	922.91	-8.2124
20	35	Biased-30krad	923.3	916.51	-6.7932
30	50	Unbiased-50krad	937.92	928.62	-9.2993
31	50	Unbiased-50krad	927.13	918.99	-8.1345
32	50	Unbiased-50krad	935.74	925.54	-10.202
33	50	Unbiased-50krad	937.43	927.85	-9.5782
34	50	Unbiased-50krad	939.03	928.76	-10.267
40	55	Biased-50krad	928.34	918.94	-9.3983
41	55	Biased-50krad	931.4	921.91	-9.4871
42	55	Biased-50krad	932.48	921.18	-11.3
43	55	Biased-50krad	928.85	916.86	-11.991
44	55	Biased-50krad	926.24	915.32	-10.922
45	100	Unbiased-100krad	926.44	910.96	-15.474
46	100	Unbiased-100krad	939.04	923.52	-15.519
47	100	Unbiased-100krad	932.54	912.9	-19.641
48	100	Unbiased-100krad	934.97	913.23	-21.734
49	100	Unbiased-100krad	934.21	916.8	-17.412
50	105	Biased-100krad	934.83	918.53	-16.301
51	105	Biased-100krad	932.26	915.59	-16.671
52	105	Biased-100krad	945.46	928.13	-17.323
53	105	Biased-100krad	933.26	916.06	-17.208
54	105	Biased-100krad	933.96	918.27	-15.688

Test Statistics (kHz)

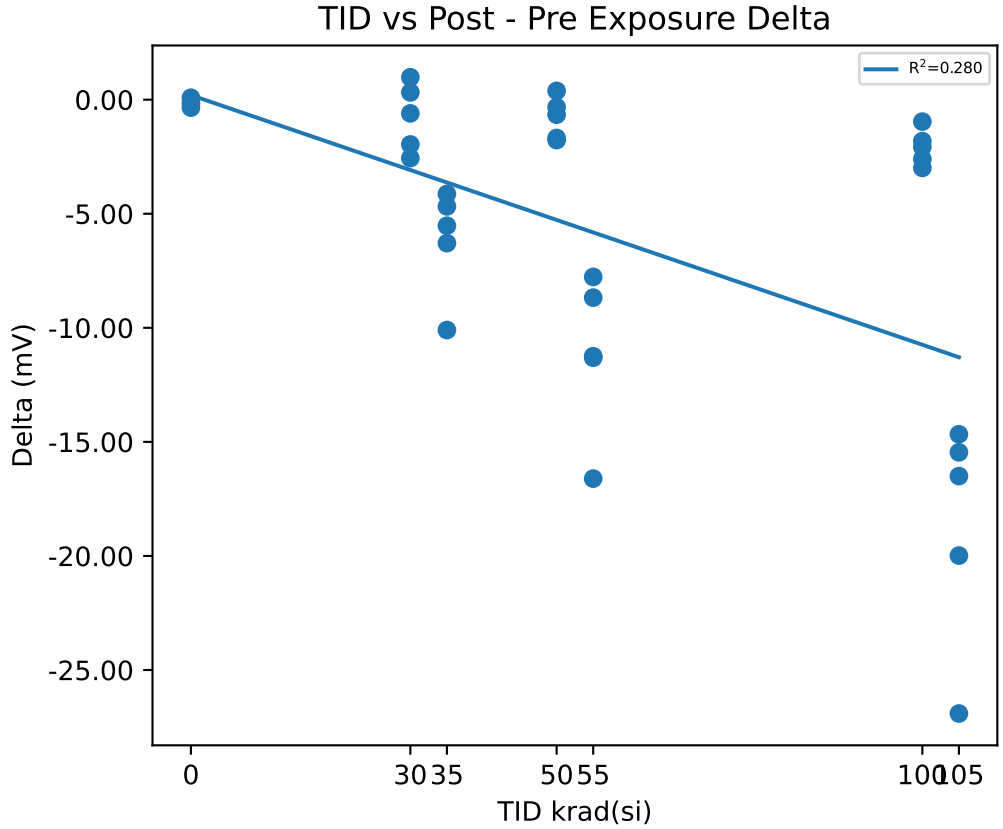
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	933.63	935.16	937.16	1.8096	931.99	933.37	934.99	1.5148	-2.1622	-1.7889	-1.572	0.3247
30	929.9	936.04	944.25	5.744	921.06	927.98	934.74	5.5582	-9.5062	-8.0596	-6.2602	1.2903
35	923.3	930.11	940.13	6.9212	916.51	923.33	933.53	6.9701	-8.2124	-6.7748	-5.8822	0.87249
50	927.13	935.45	939.03	4.7995	918.99	925.95	928.76	4.0986	-10.267	-9.4961	-8.1345	0.86476
55	926.24	929.46	932.48	2.4935	915.32	918.84	921.91	2.7953	-11.991	-10.62	-9.3983	1.1412
100	926.44	933.44	939.04	4.5856	910.96	915.48	923.52	4.9614	-21.734	-17.956	-15.474	2.7162
105	932.26	935.95	945.46	5.3949	915.59	919.32	928.13	5.0987	-17.323	-16.638	-15.688	0.67287

Device Test: 33.1 _Enable|RisingThreshold/EN1/3/3///90.9/634//0///@EN_VTH_RISING

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

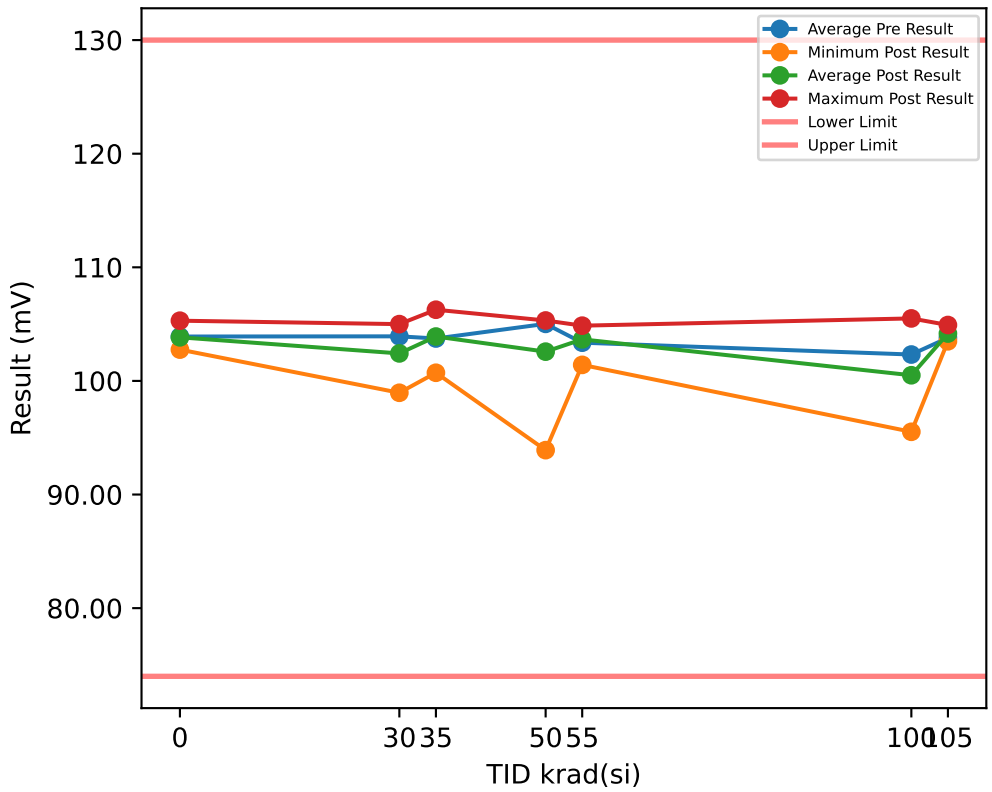
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	606.12	605.97	-0.1535
2	0	CU2	602.86	602.51	-0.348
3	0	CU3	605.24	605.33	0.084
11	30	Unbiased-30krad	607.05	608.03	0.9819
12	30	Unbiased-30krad	611.53	610.93	-0.6004
13	30	Unbiased-30krad	605.59	605.91	0.32
14	30	Unbiased-30krad	607.83	605.87	-1.9613
15	30	Unbiased-30krad	604.79	602.23	-2.5603
16	35	Biased-30krad	606.31	602.18	-4.1334
17	35	Biased-30krad	605.45	595.35	-10.098
18	35	Biased-30krad	609.05	602.76	-6.2883
19	35	Biased-30krad	609.04	603.52	-5.5255
20	35	Biased-30krad	607.95	603.28	-4.6764
30	50	Unbiased-50krad	603.76	604.15	0.387
31	50	Unbiased-50krad	609.24	607.47	-1.7719
32	50	Unbiased-50krad	607.63	605.95	-1.6789
33	50	Unbiased-50krad	605.25	604.92	-0.3287
34	50	Unbiased-50krad	604.34	603.68	-0.6569
40	55	Biased-50krad	608.4	597.16	-11.245
41	55	Biased-50krad	604.87	588.26	-16.611
42	55	Biased-50krad	608.59	599.91	-8.6774
43	55	Biased-50krad	609	597.69	-11.309
44	55	Biased-50krad	606.63	598.86	-7.769
45	100	Unbiased-100krad	607.97	604.98	-2.9903
46	100	Unbiased-100krad	606.75	604.93	-1.8181
47	100	Unbiased-100krad	606.32	603.72	-2.5977
48	100	Unbiased-100krad	606.47	604.4	-2.0657
49	100	Unbiased-100krad	609.91	608.95	-0.9617
50	105	Biased-100krad	608.86	592.36	-16.501
51	105	Biased-100krad	604.58	577.67	-26.907
52	105	Biased-100krad	606.99	592.32	-14.666
53	105	Biased-100krad	605.74	590.28	-15.458
54	105	Biased-100krad	603.3	583.32	-19.985

Test Statistics (mV)

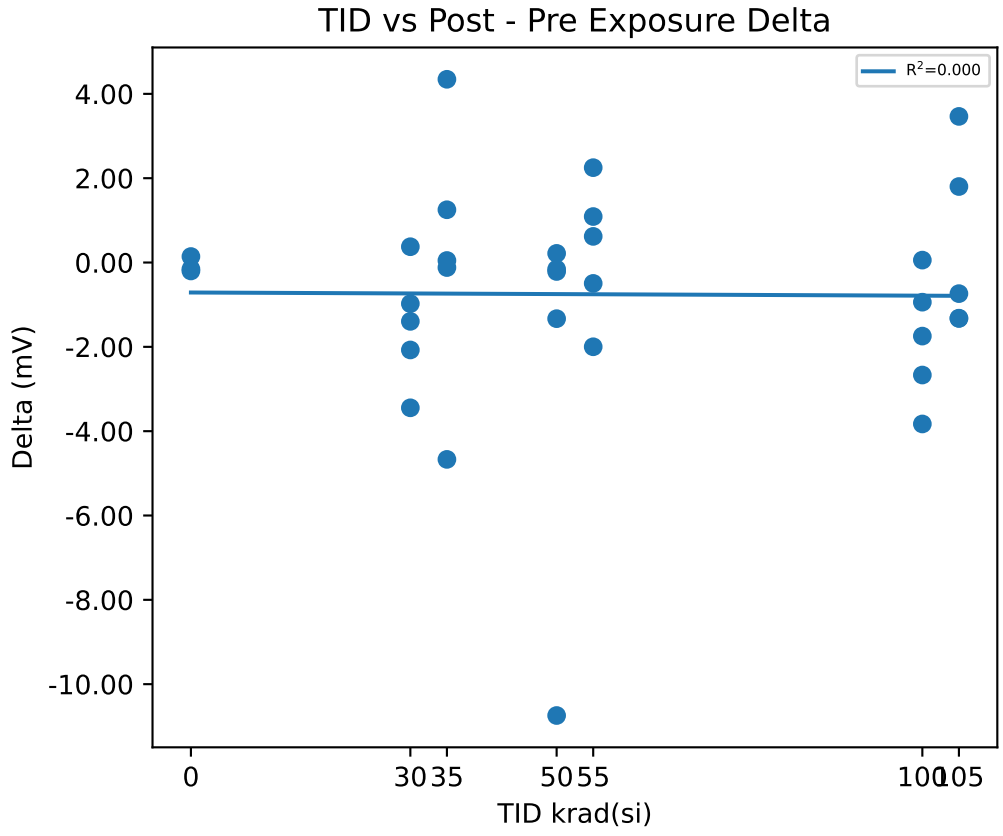
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	602.86	604.74	606.12	1.6891	602.51	604.6	605.97	1.8399	-0.348	-0.13917	0.084	0.21636
30	604.79	607.36	611.53	2.6174	602.23	606.59	610.93	3.1964	-2.5603	-0.76402	0.9819	1.4925
35	605.45	607.56	609.05	1.6278	595.35	601.42	603.52	3.4311	-10.098	-6.1444	-4.1334	2.3578
50	603.76	606.04	609.24	2.3172	603.68	605.23	607.47	1.5164	-1.7719	-0.80988	0.387	0.91762
55	604.87	607.5	609	1.7249	588.26	596.37	599.91	4.6597	-16.611	-11.122	-7.769	3.4422
100	606.32	607.48	609.91	1.5065	603.72	605.4	608.95	2.0516	-2.9903	-2.0867	-0.9617	0.77715
105	603.3	605.89	608.86	2.1472	577.67	587.19	592.36	6.4839	-26.907	-18.703	-14.666	5.0154

Device Test: 33.10 _Enable|Hys/EN2/3/3///90.9/634//0///@EN_VTH_HYST

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

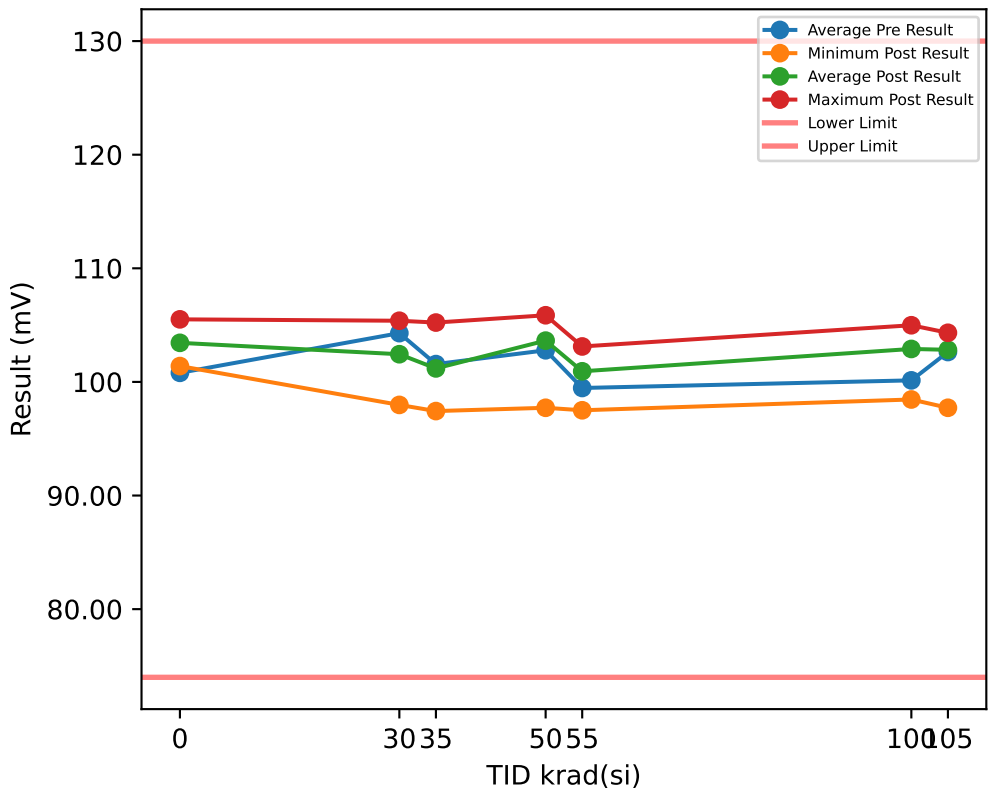
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	102.96	102.76	-0.2003
2	0	CU2	105.16	105.3	0.1421
3	0	CU3	103.61	103.45	-0.1536
11	30	Unbiased-30krad	100.35	98.957	-1.3956
12	30	Unbiased-30krad	105.89	102.44	-3.4457
13	30	Unbiased-30krad	104.67	102.6	-2.0736
14	30	Unbiased-30krad	104.08	103.11	-0.976
15	30	Unbiased-30krad	104.62	105	0.3747
16	35	Biased-30krad	106.39	106.27	-0.1192
17	35	Biased-30krad	101.42	102.67	1.2515
18	35	Biased-30krad	101.22	105.57	4.3457
19	35	Biased-30krad	105.39	100.72	-4.669
20	35	Biased-30krad	104.26	104.31	0.0481
30	50	Unbiased-50krad	104.65	93.907	-10.743
31	50	Unbiased-50krad	106.63	105.29	-1.3317
32	50	Unbiased-50krad	103	103.21	0.2168
33	50	Unbiased-50krad	105.36	105.15	-0.2126
34	50	Unbiased-50krad	105.48	105.32	-0.1569
40	55	Biased-50krad	103.64	104.73	1.0905
41	55	Biased-50krad	105.36	104.86	-0.4952
42	55	Biased-50krad	103.41	101.41	-1.9981
43	55	Biased-50krad	101.89	102.51	0.6199
44	55	Biased-50krad	102.53	104.78	2.2499
45	100	Unbiased-100krad	103.55	100.89	-2.6682
46	100	Unbiased-100krad	105.77	104.83	-0.9406
47	100	Unbiased-100krad	105.44	105.5	0.0573
48	100	Unbiased-100krad	99.35	95.521	-3.8288
49	100	Unbiased-100krad	97.499	95.754	-1.7449
50	105	Biased-100krad	104.81	103.49	-1.3202
51	105	Biased-100krad	101.37	104.83	3.4654
52	105	Biased-100krad	102.23	104.03	1.8025
53	105	Biased-100krad	104.91	103.59	-1.3261
54	105	Biased-100krad	105.66	104.92	-0.7377

Test Statistics (mV)

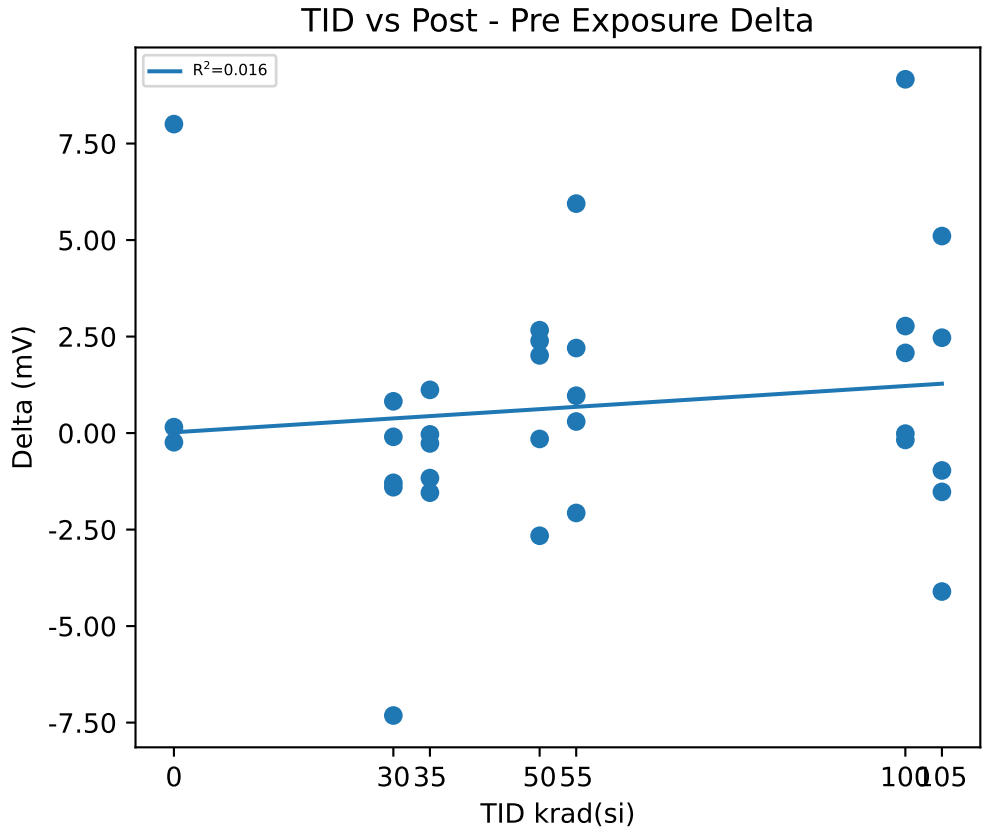
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	102.96	103.91	105.16	1.1311	102.76	103.84	105.3	1.3146	-0.2003	-0.0706	0.1421	0.18568
30	100.35	103.92	105.89	2.1032	98.957	102.42	105	2.1879	-3.4457	-1.5032	0.3747	1.4067
35	101.22	103.73	106.39	2.3291	100.72	103.91	106.27	2.2463	-4.669	0.17142	4.3457	3.245
50	103	105.02	106.63	1.3351	93.907	102.58	105.32	4.9265	-10.743	-2.4456	0.2168	4.6746
55	101.89	103.37	105.36	1.3148	101.41	103.66	104.86	1.5983	-1.9981	0.2934	2.2499	1.6158
100	97.499	102.32	105.77	3.7164	95.521	100.5	105.5	4.7753	-3.8288	-1.825	0.0573	1.5048
105	101.37	103.79	105.66	1.8779	103.49	104.17	104.92	0.67596	-1.3261	0.37678	3.4654	2.156

Device Test: 33.11 _Enable|Hys/EN3/3/3///90.9/634//0///@EN_VTH_HYST

TID vs Result Stats



TID vs Post - Pre Exposure Delta



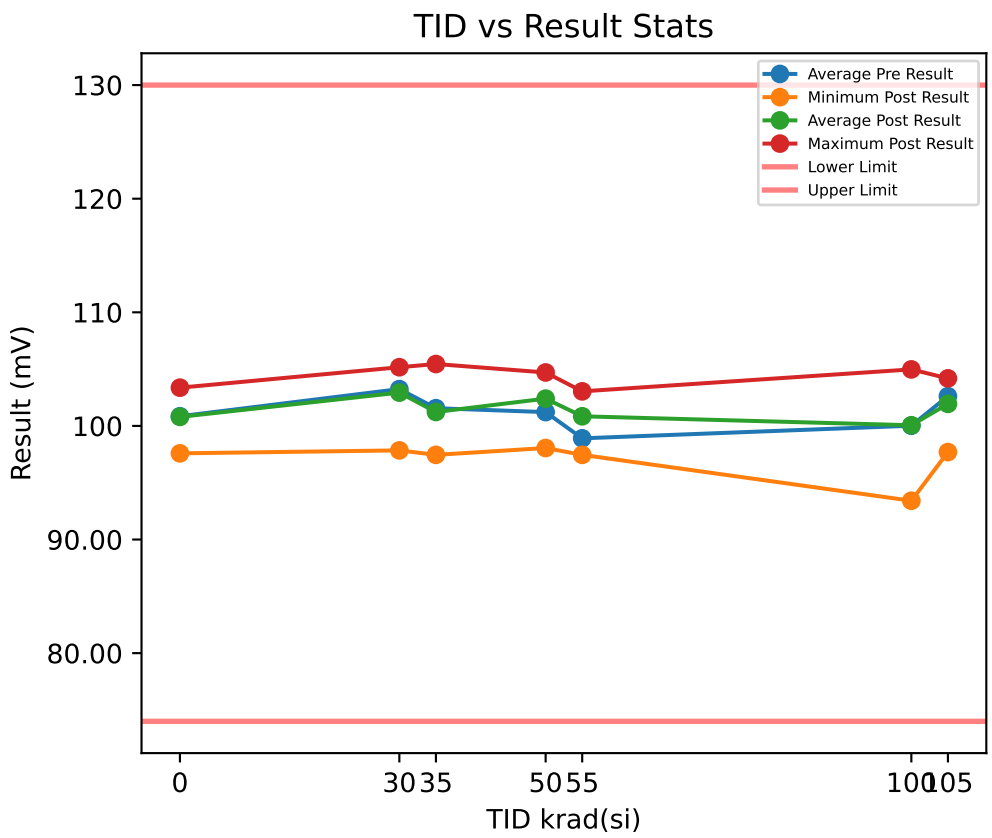
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

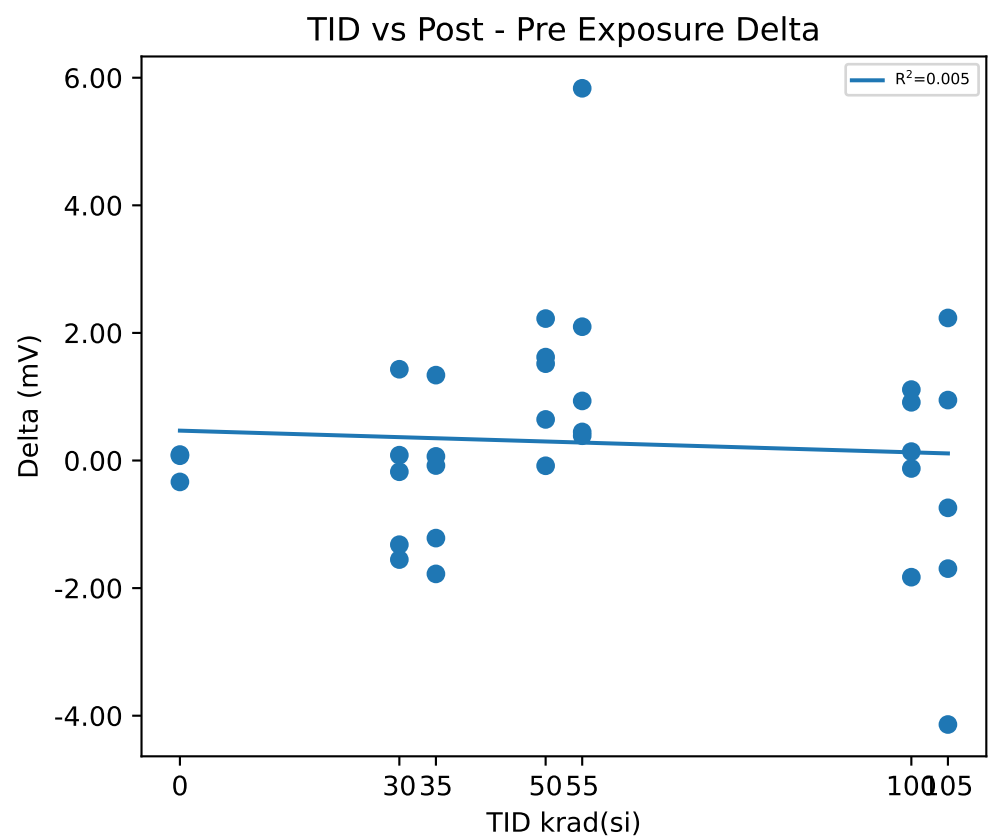
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.65	103.42	-0.2374
2	0	CU2	101.24	101.39	0.1533
3	0	CU3	97.505	105.51	8.0033
11	30	Unbiased-30krad	103.49	102.09	-1.4027
12	30	Unbiased-30krad	103.55	103.46	-0.0975
13	30	Unbiased-30krad	104.57	103.28	-1.2887
14	30	Unbiased-30krad	104.56	105.39	0.8225
15	30	Unbiased-30krad	105.29	97.977	-7.3163
16	35	Biased-30krad	105.49	105.22	-0.2683
17	35	Biased-30krad	104.42	102.87	-1.5438
18	35	Biased-30krad	97.811	98.93	1.119
19	35	Biased-30krad	98.6	97.434	-1.1664
20	35	Biased-30krad	101.52	101.48	-0.034
30	50	Unbiased-50krad	95.711	97.723	2.0118
31	50	Unbiased-50krad	102.99	105.66	2.6657
32	50	Unbiased-50krad	106.02	105.87	-0.1521
33	50	Unbiased-50krad	105.81	103.15	-2.6597
34	50	Unbiased-50krad	103.38	105.77	2.3887
40	55	Biased-50krad	97.204	97.504	0.2994
41	55	Biased-50krad	100.66	102.87	2.2026
42	55	Biased-50krad	105.19	103.12	-2.0693
43	55	Biased-50krad	96.135	102.08	5.9441
44	55	Biased-50krad	98.137	99.105	0.9677
45	100	Unbiased-100krad	98.632	98.454	-0.1778
46	100	Unbiased-100krad	105	104.99	-0.0143
47	100	Unbiased-100krad	102.86	104.93	2.0771
48	100	Unbiased-100krad	92.525	101.69	9.1646
49	100	Unbiased-100krad	101.67	104.45	2.7721
50	105	Biased-100krad	105.81	104.29	-1.5232
51	105	Biased-100krad	101.62	104.09	2.4704
52	105	Biased-100krad	101.83	97.724	-4.1049
53	105	Biased-100krad	104.68	103.71	-0.9683
54	105	Biased-100krad	99.221	104.32	5.1035

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.505	100.8	103.65	3.0987	101.39	103.44	105.51	2.0568	-0.2374	2.6397	8.0033	4.6491
30	103.49	104.29	105.29	0.76478	97.977	102.44	105.39	2.7596	-7.3163	-1.8565	0.8225	3.1863
35	97.811	101.57	105.49	3.4079	97.434	101.19	105.22	3.0992	-1.5438	-0.3787	1.119	1.0431
50	95.711	102.78	106.02	4.1855	97.723	103.63	105.87	3.4935	-2.6597	0.85088	2.6657	2.2548
55	96.135	99.466	105.19	3.6118	97.504	100.94	103.12	2.4972	-2.0693	1.4689	5.9441	2.9455
100	92.525	100.14	105	4.838	98.454	102.9	104.99	2.8334	-0.1778	2.7643	9.1646	3.8017
105	99.221	102.63	105.81	2.6286	97.724	102.83	104.32	2.8635	-4.1049	0.1955	5.1035	3.6078

Device Test: 33.12 _Enable|Hys/EN4/3/3///90.9/634//0///@EN_VTH_HYST





Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

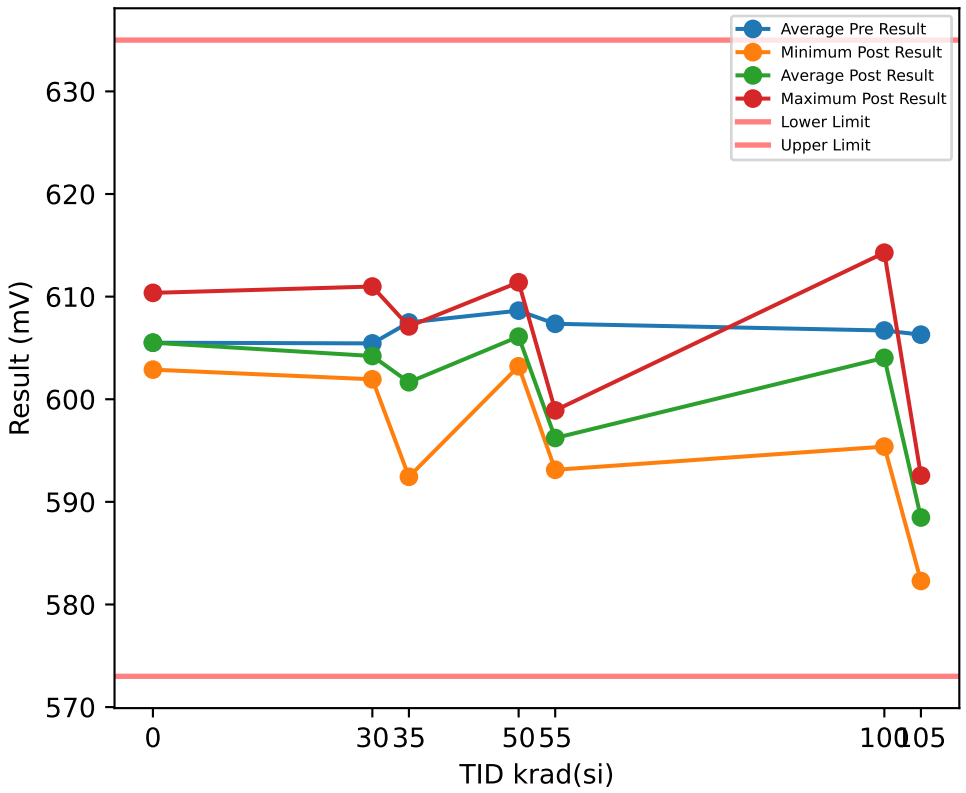
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.7	103.37	-0.3356
2	0	CU2	101.34	101.43	0.0935
3	0	CU3	97.512	97.587	0.075
11	30	Unbiased-30krad	103.74	105.17	1.4305
12	30	Unbiased-30krad	103.61	103.43	-0.1762
13	30	Unbiased-30krad	104.66	103.34	-1.3192
14	30	Unbiased-30krad	104.8	104.88	0.0838
15	30	Unbiased-30krad	99.399	97.847	-1.5528
16	35	Biased-30krad	105.53	105.45	-0.0789
17	35	Biased-30krad	104.41	102.64	-1.7772
18	35	Biased-30krad	97.748	99.086	1.3383
19	35	Biased-30krad	98.669	97.453	-1.2162
20	35	Biased-30krad	101.44	101.5	0.0646
30	50	Unbiased-50krad	95.83	98.055	2.2247
31	50	Unbiased-50krad	103.08	104.7	1.6207
32	50	Unbiased-50krad	102.21	102.12	-0.0824
33	50	Unbiased-50krad	101.56	103.08	1.5179
34	50	Unbiased-50krad	103.41	104.05	0.6441
40	55	Biased-50krad	97.064	97.452	0.3882
41	55	Biased-50krad	100.78	102.88	2.0974
42	55	Biased-50krad	102.59	103.04	0.4482
43	55	Biased-50krad	96.088	101.92	5.8344
44	55	Biased-50krad	98.008	98.942	0.934
45	100	Unbiased-100krad	98.574	98.449	-0.1251
46	100	Unbiased-100krad	104.83	104.97	0.1397
47	100	Unbiased-100krad	102.61	103.73	1.1118
48	100	Unbiased-100krad	92.501	93.413	0.9123
49	100	Unbiased-100krad	101.56	99.73	-1.8287
50	105	Biased-100krad	105.88	104.18	-1.6945
51	105	Biased-100krad	101.63	103.86	2.2346
52	105	Biased-100krad	101.84	97.698	-4.1379
53	105	Biased-100krad	104.54	103.8	-0.7417
54	105	Biased-100krad	99.211	100.16	0.9474

Test Statistics (mV)

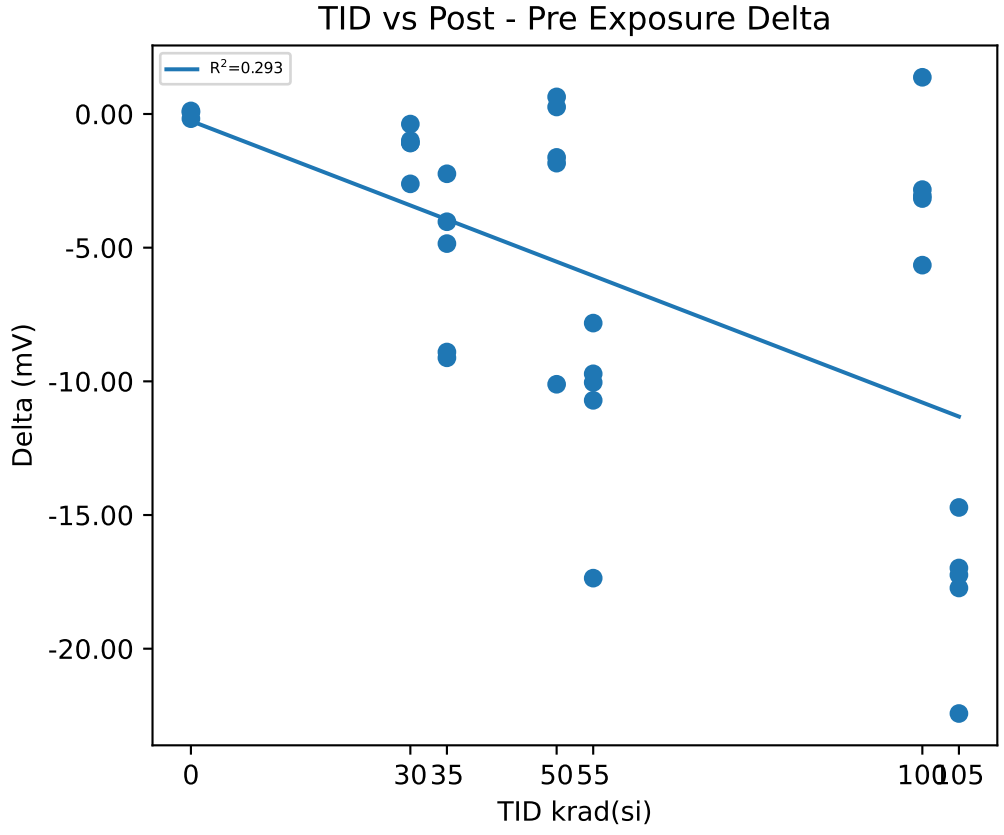
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.512	100.85	103.7	3.1241	97.587	100.8	103.37	2.9423	-0.3356	-0.0557	0.0935	0.24258
30	99.399	103.24	104.8	2.2119	97.847	102.93	105.17	2.9612	-1.5528	-0.30678	1.4305	1.2006
35	97.748	101.56	105.53	3.4202	97.453	101.23	105.45	3.1109	-1.7772	-0.33388	1.3383	1.2126
50	95.83	101.22	103.41	3.0981	98.055	102.4	104.7	2.6196	-0.0824	1.185	2.2247	0.90561
55	96.088	98.907	102.59	2.7048	97.452	100.85	103.04	2.513	0.3882	1.9404	5.8344	2.2824
100	92.501	100.02	104.83	4.7673	93.413	100.06	104.97	4.5956	-1.8287	0.042	1.1118	1.1661
105	99.211	102.62	105.88	2.6238	97.698	101.94	104.18	2.8875	-4.1379	-0.67842	2.2346	2.4563

Device Test: 33.2 _Enable|RisingThreshold/EN2/3/3///90.9/634//0///@EN_VTH_RISING

TID vs Result Stats



TID vs Post - Pre Exposure Delta



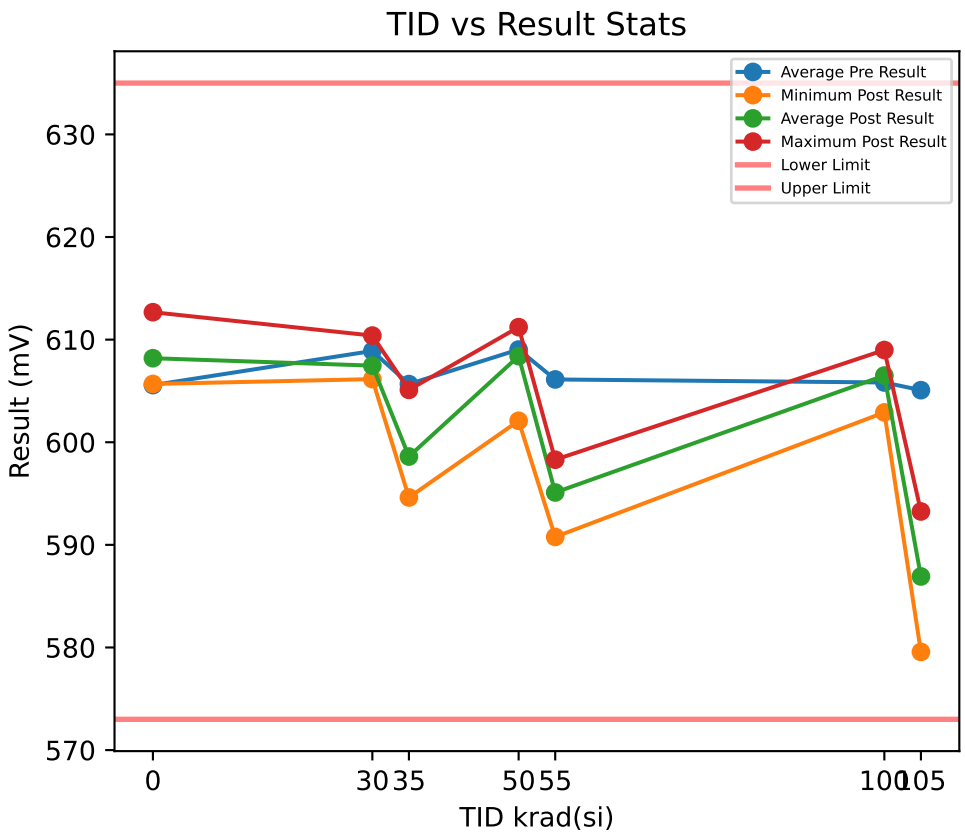
Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

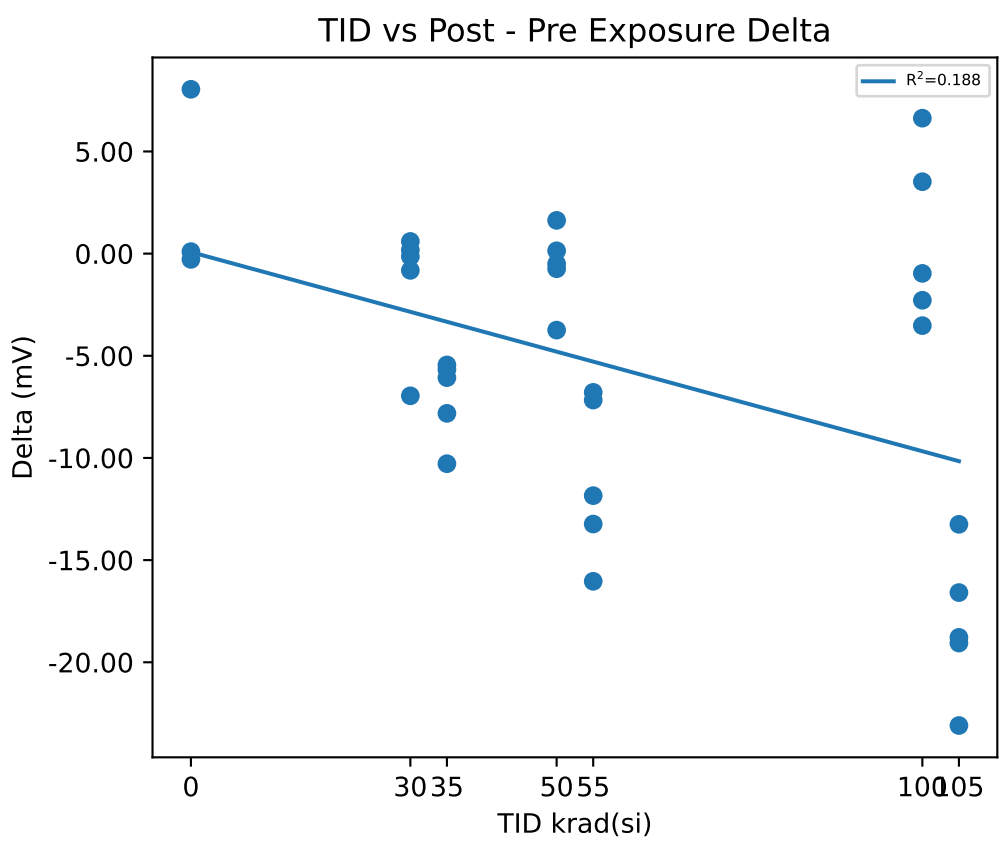
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	603.46	603.28	-0.1753
2	0	CU2	610.25	610.37	0.1149
3	0	CU3	602.82	602.89	0.0636
11	30	Unbiased-30krad	602.32	601.94	-0.3765
12	30	Unbiased-30krad	612.07	610.98	-1.0826
13	30	Unbiased-30krad	603.82	602.74	-1.0816
14	30	Unbiased-30krad	605.84	603.23	-2.6131
15	30	Unbiased-30krad	603.17	602.18	-0.9918
16	35	Biased-30krad	607.62	603.59	-4.0303
17	35	Biased-30krad	601.56	592.44	-9.1198
18	35	Biased-30krad	609.34	607.1	-2.2363
19	35	Biased-30krad	612.59	603.69	-8.903
20	35	Biased-30krad	606.3	601.46	-4.8476
30	50	Unbiased-50krad	614.49	604.38	-10.109
31	50	Unbiased-50krad	610.76	611.4	0.6397
32	50	Unbiased-50krad	604.83	603.21	-1.6233
33	50	Unbiased-50krad	605.24	603.4	-1.8389
34	50	Unbiased-50krad	607.85	608.12	0.262
40	55	Biased-50krad	608.14	598.1	-10.041
41	55	Biased-50krad	610.48	593.12	-17.361
42	55	Biased-50krad	606.15	595.44	-10.71
43	55	Biased-50krad	605.26	595.54	-9.7184
44	55	Biased-50krad	606.73	598.91	-7.8211
45	100	Unbiased-100krad	608.27	605.22	-3.0528
46	100	Unbiased-100krad	612.91	614.28	1.3729
47	100	Unbiased-100krad	609.18	606.02	-3.1628
48	100	Unbiased-100krad	601.04	595.38	-5.6536
49	100	Unbiased-100krad	602.1	599.27	-2.8284
50	105	Biased-100krad	607.35	590.37	-16.981
51	105	Biased-100krad	604.71	582.29	-22.424
52	105	Biased-100krad	607.28	592.56	-14.717
53	105	Biased-100krad	607.29	590.05	-17.241
54	105	Biased-100krad	604.84	587.11	-17.729

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	602.82	605.51	610.25	4.1179	602.89	605.51	610.37	4.2089	-0.1753	0.0010667	0.1149	0.15488
30	602.32	605.44	612.07	3.9238	601.94	604.21	610.98	3.8171	-2.6131	-1.2291	-0.3765	0.82794
35	601.56	607.48	612.59	4.062	592.44	601.66	607.1	5.5327	-9.1198	-5.8274	-2.2363	3.0572
50	604.83	608.63	614.49	4.0418	603.21	606.1	611.4	3.5611	-10.109	-2.534	0.6397	4.3758
55	605.26	607.35	610.48	2.0389	593.12	596.22	598.91	2.3151	-17.361	-11.13	-7.8211	3.6445
100	601.04	606.7	612.91	5.0107	595.38	604.03	614.28	7.2089	-5.6536	-2.6649	1.3729	2.5328
105	604.71	606.29	607.35	1.3879	582.29	588.47	592.56	3.9655	-22.424	-17.819	-14.717	2.8226

Device Test: 33.3 _Enable|RisingThreshold/EN3/3/3///90.9/634//0///@EN_VTH_RISING





Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

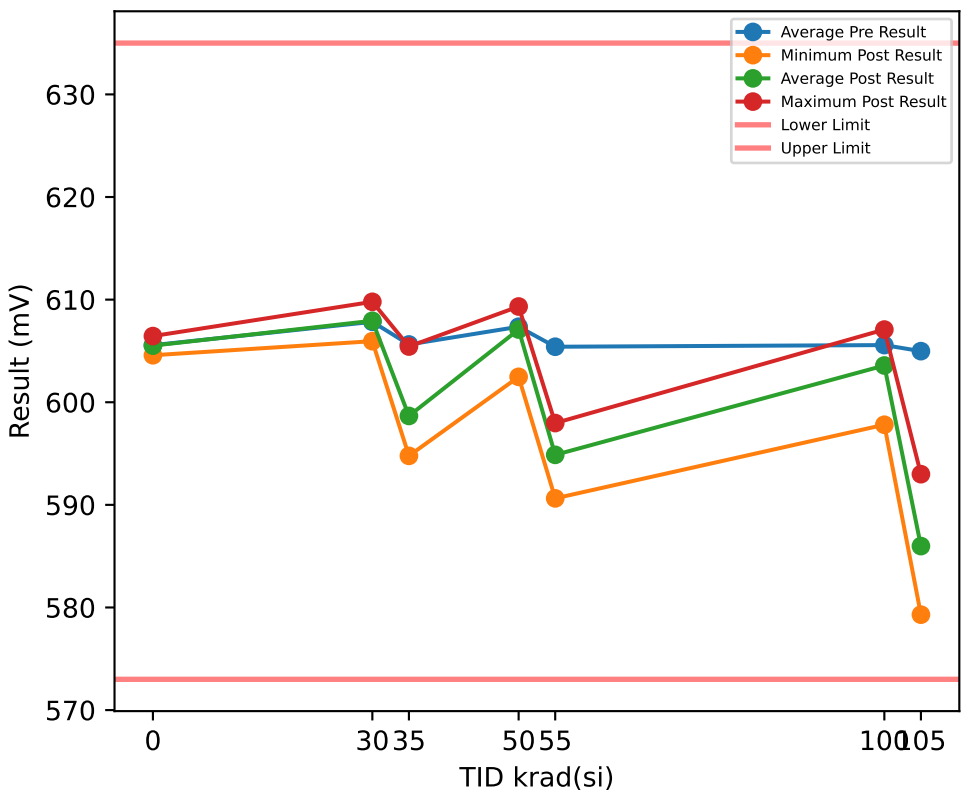
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	605.96	605.68	-0.282
2	0	CU2	606.12	606.21	0.0978
3	0	CU3	604.63	612.67	8.043
11	30	Unbiased-30krad	606.97	606.15	-0.819
12	30	Unbiased-30krad	606.77	606.63	-0.1403
13	30	Unbiased-30krad	607.33	607.93	0.5969
14	30	Unbiased-30krad	610.21	610.39	0.1813
15	30	Unbiased-30krad	613.19	606.23	-6.9587
16	35	Biased-30krad	611.17	605.1	-6.0691
17	35	Biased-30krad	606.53	596.25	-10.282
18	35	Biased-30krad	603.79	598.35	-5.4468
19	35	Biased-30krad	602.44	594.62	-7.8173
20	35	Biased-30krad	604.4	598.73	-5.6731
30	50	Unbiased-50krad	600.46	602.09	1.6272
31	50	Unbiased-50krad	610.89	610.4	-0.496
32	50	Unbiased-50krad	611.96	611.22	-0.7397
33	50	Unbiased-50krad	612.4	608.66	-3.7433
34	50	Unbiased-50krad	609.46	609.6	0.1387
40	55	Biased-50krad	604.54	592.7	-11.845
41	55	Biased-50krad	606.81	590.77	-16.037
42	55	Biased-50krad	610.41	597.17	-13.234
43	55	Biased-50krad	605.47	598.3	-7.1679
44	55	Biased-50krad	603.37	596.58	-6.7892
45	100	Unbiased-100krad	606.43	602.91	-3.5239
46	100	Unbiased-100krad	609.46	607.18	-2.2816
47	100	Unbiased-100krad	608.25	607.29	-0.967
48	100	Unbiased-100krad	599.51	606.14	6.6293
49	100	Unbiased-100krad	605.47	608.99	3.5203
50	105	Biased-100krad	609.84	593.26	-16.588
51	105	Biased-100krad	602.66	579.57	-23.095
52	105	Biased-100krad	603.63	584.57	-19.059
53	105	Biased-100krad	604.42	585.64	-18.781
54	105	Biased-100krad	604.81	591.56	-13.249

Test Statistics (mV)

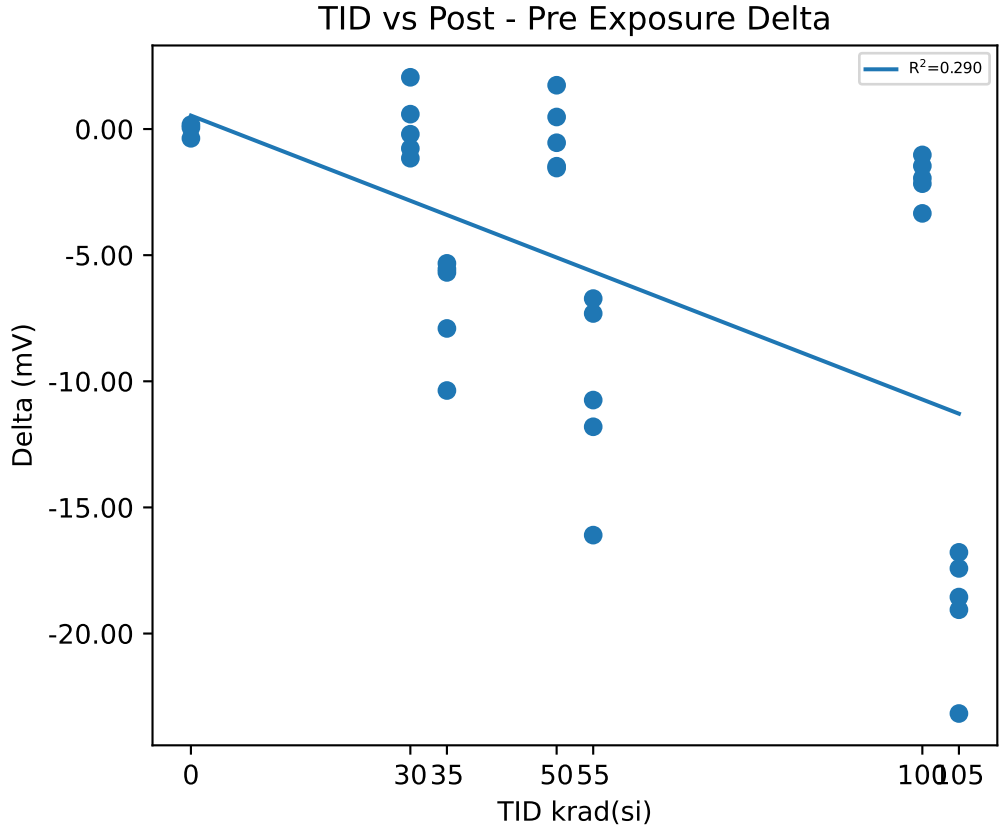
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	604.63	605.57	606.12	0.81776	605.68	608.19	612.67	3.8918	-0.282	2.6196	8.043	4.7006
30	606.77	608.89	613.19	2.777	606.15	607.47	610.39	1.7853	-6.9587	-1.428	0.5969	3.1348
35	602.44	605.67	611.17	3.4129	594.62	598.61	605.1	3.9915	-10.282	-7.0576	-5.4468	2.0287
50	600.46	609.03	612.4	4.9237	602.09	608.39	611.22	3.6483	-3.7433	-0.64262	1.6272	1.9626
55	603.37	606.12	610.41	2.7083	590.77	595.1	598.3	3.2094	-16.037	-11.015	-6.7892	3.9841
100	599.51	605.82	609.46	3.858	602.91	606.5	608.99	2.2536	-3.5239	0.67542	6.6293	4.2608
105	602.66	605.07	609.84	2.7903	579.57	586.92	593.26	5.5436	-23.095	-18.154	-13.249	3.6104

Device Test: 33.4 _Enable|RisingThreshold/EN4/3/3///90.9/634//0///@EN_VTH_RISING

TID vs Result Stats



TID vs Post - Pre Exposure Delta



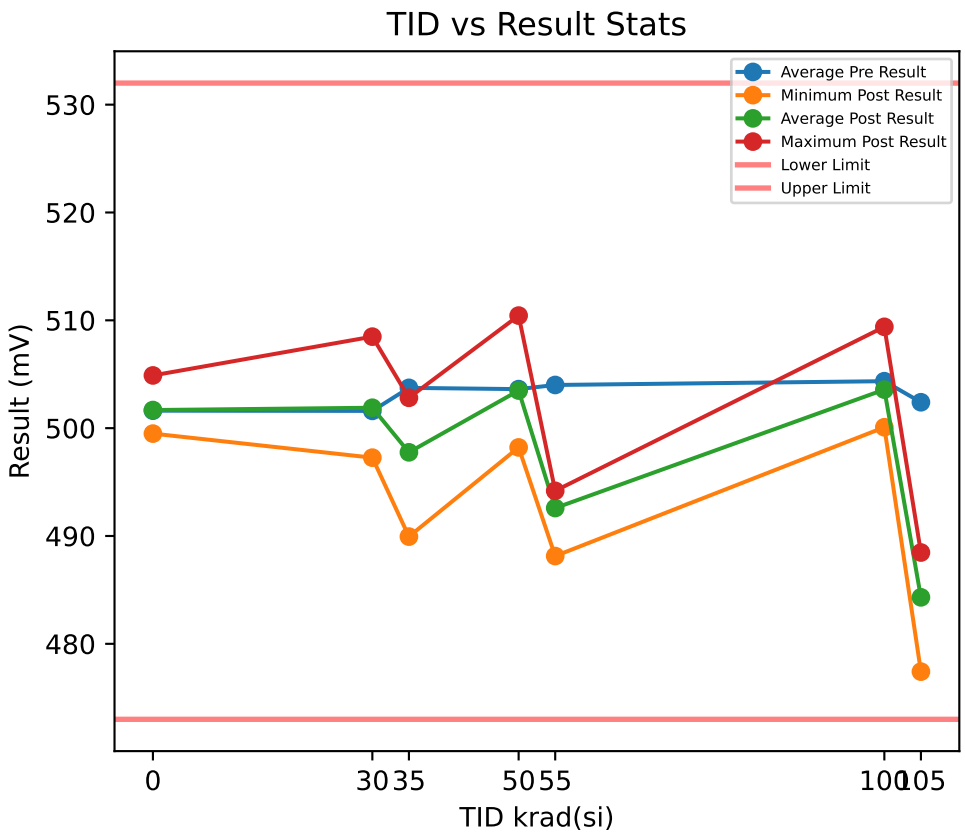
Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

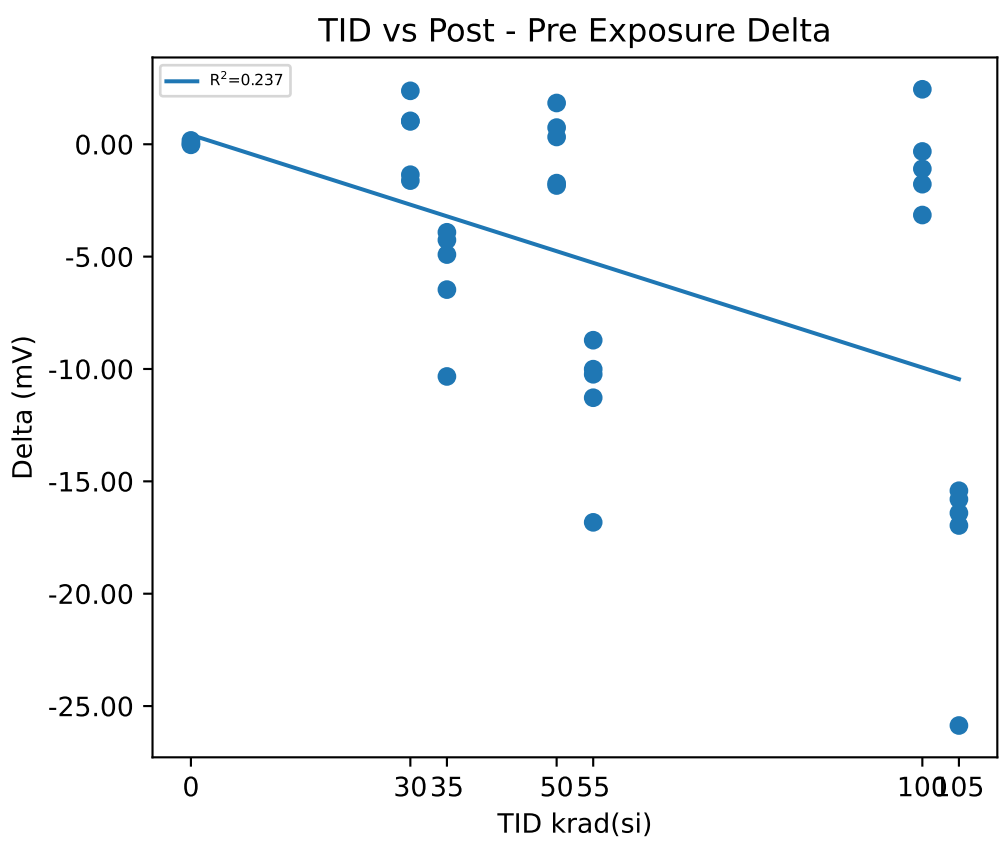
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	605.89	605.52	-0.3671
2	0	CU2	606.39	606.45	0.0575
3	0	CU3	604.41	604.58	0.172
11	30	Unbiased-30krad	607.32	609.37	2.0518
12	30	Unbiased-30krad	606.66	606.45	-0.2049
13	30	Unbiased-30krad	607.55	608.14	0.5901
14	30	Unbiased-30krad	610.56	609.79	-0.7694
15	30	Unbiased-30krad	607.11	605.95	-1.1568
16	35	Biased-30krad	611.11	605.43	-5.6841
17	35	Biased-30krad	606.32	595.96	-10.365
18	35	Biased-30krad	603.88	598.56	-5.3247
19	35	Biased-30krad	602.68	594.78	-7.9049
20	35	Biased-30krad	604.15	598.6	-5.5493
30	50	Unbiased-50krad	600.74	602.48	1.7365
31	50	Unbiased-50krad	610.8	609.33	-1.4737
32	50	Unbiased-50krad	607.95	607.41	-0.543
33	50	Unbiased-50krad	608.02	608.49	0.4777
34	50	Unbiased-50krad	609.28	607.73	-1.5465
40	55	Biased-50krad	604.29	592.49	-11.803
41	55	Biased-50krad	606.73	590.63	-16.098
42	55	Biased-50krad	607.65	596.91	-10.744
43	55	Biased-50krad	605.28	597.97	-7.3123
44	55	Biased-50krad	603.09	596.37	-6.7211
45	100	Unbiased-100krad	606.19	602.85	-3.3433
46	100	Unbiased-100krad	609.25	607.08	-2.1656
47	100	Unbiased-100krad	607.95	606.01	-1.9468
48	100	Unbiased-100krad	599.27	597.81	-1.4628
49	100	Unbiased-100krad	605.19	604.16	-1.0253
50	105	Biased-100krad	609.77	592.99	-16.781
51	105	Biased-100krad	602.47	579.3	-23.17
52	105	Biased-100krad	603.79	584.74	-19.056
53	105	Biased-100krad	604.19	585.64	-18.554
54	105	Biased-100krad	604.67	587.25	-17.418

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	604.41	605.56	606.39	1.031	604.58	605.52	606.45	0.93402	-0.3671	-0.045867	0.172	0.28403
30	606.66	607.84	610.56	1.5546	605.95	607.94	609.79	1.7084	-1.1568	0.10216	2.0518	1.2726
35	602.68	605.63	611.11	3.335	594.78	598.66	605.43	4.1298	-10.365	-6.9657	-5.3247	2.1668
50	600.74	607.36	610.8	3.8776	602.48	607.09	609.33	2.6826	-1.5465	-0.2698	1.7365	1.3909
55	603.09	605.41	607.65	1.8327	590.63	594.87	597.97	3.1479	-16.098	-10.536	-6.7211	3.7926
100	599.27	605.57	609.25	3.8544	597.81	603.58	607.08	3.6175	-3.3433	-1.9888	-1.0253	0.87646
105	602.47	604.98	609.77	2.8013	579.3	585.98	592.99	4.9258	-23.17	-18.996	-16.781	2.5009

Device Test: 33.5 _Enable|FallingThreshold/EN1/3/3///90.9/634//0///@EN_VTH_FALLING





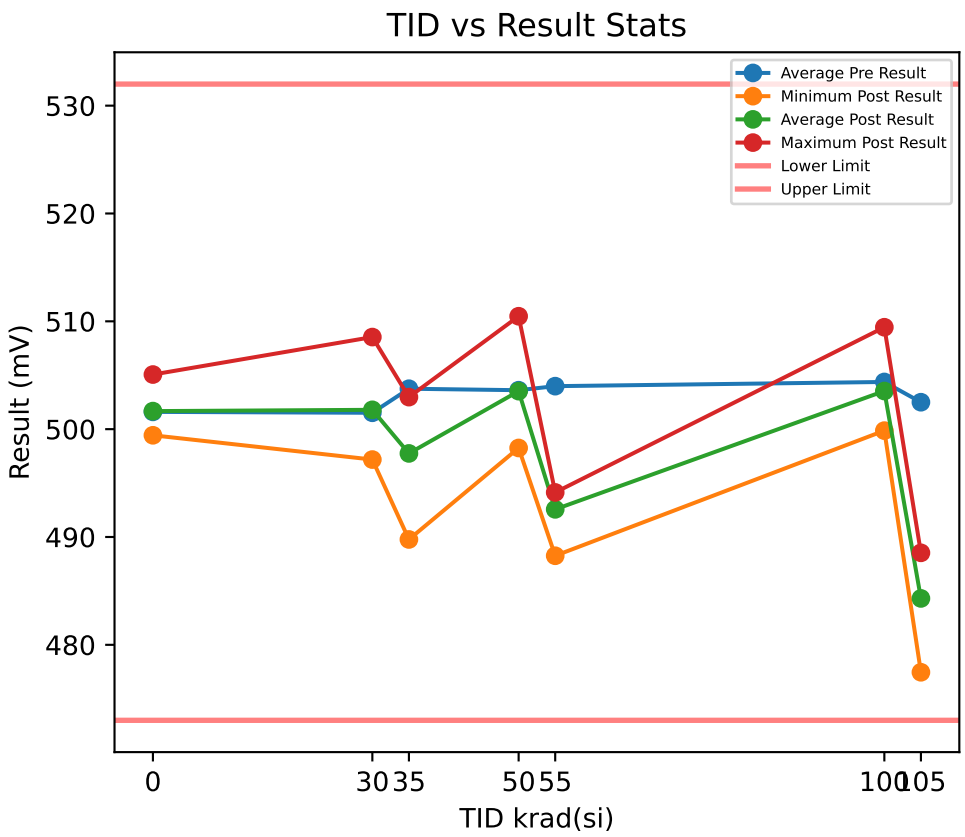
Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

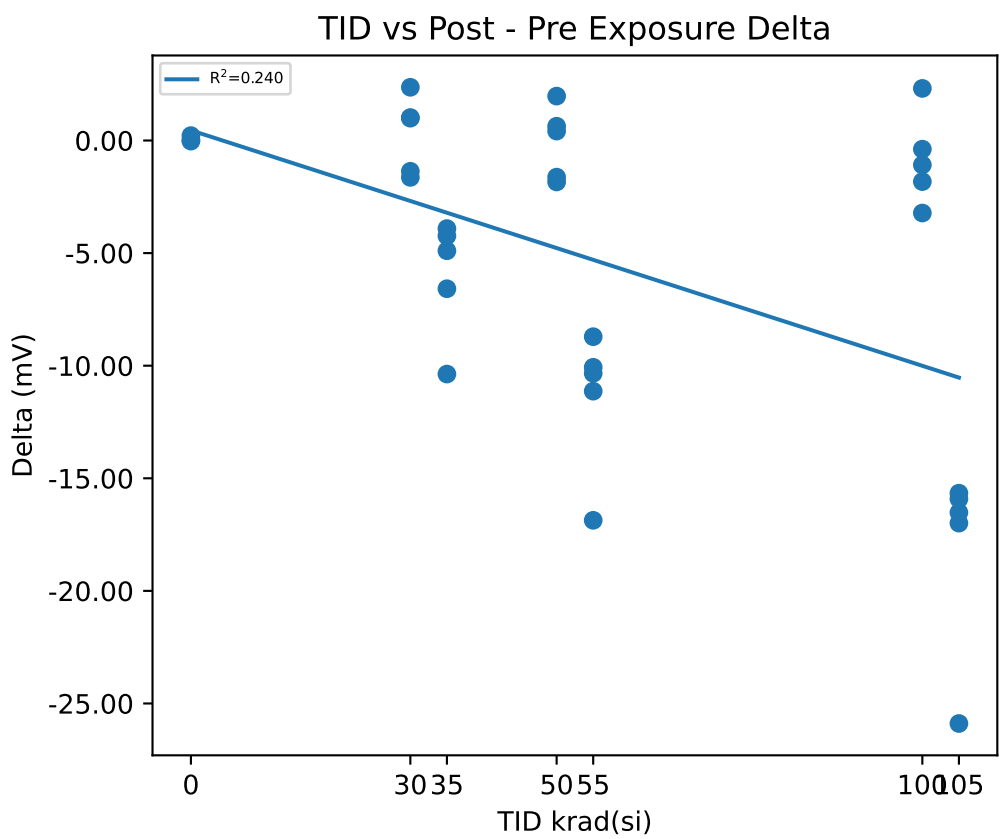
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	500.63	500.66	0.0281
2	0	CU2	504.91	504.89	-0.0255
3	0	CU3	499.32	499.49	0.1709
11	30	Unbiased-30krad	502.15	503.17	1.0177
12	30	Unbiased-30krad	506.11	508.49	2.3772
13	30	Unbiased-30krad	499.23	500.27	1.0415
14	30	Unbiased-30krad	501.89	500.27	-1.6175
15	30	Unbiased-30krad	498.62	497.26	-1.3549
16	35	Biased-30krad	501.2	497.29	-3.9169
17	35	Biased-30krad	500.28	489.94	-10.333
18	35	Biased-30krad	507.92	501.45	-6.4681
19	35	Biased-30krad	507.07	502.81	-4.2605
20	35	Biased-30krad	502.21	497.3	-4.9093
30	50	Unbiased-50krad	509.7	510.44	0.7417
31	50	Unbiased-50krad	504.11	505.94	1.8359
32	50	Unbiased-50krad	502.02	500.19	-1.836
33	50	Unbiased-50krad	499.94	498.21	-1.7297
34	50	Unbiased-50krad	502.33	502.65	0.3238
40	55	Biased-50krad	504.63	493.35	-11.279
41	55	Biased-50krad	504.96	488.14	-16.825
42	55	Biased-50krad	502.91	494.19	-8.7196
43	55	Biased-50krad	503.43	493.19	-10.236
44	55	Biased-50krad	504.09	494.08	-10.008
45	100	Unbiased-100krad	504.59	504.27	-0.3204
46	100	Unbiased-100krad	506.95	509.4	2.4458
47	100	Unbiased-100krad	503.61	500.46	-3.1493
48	100	Unbiased-100krad	501.86	500.08	-1.7769
49	100	Unbiased-100krad	504.76	503.67	-1.0933
50	105	Biased-100krad	502.49	487.07	-15.418
51	105	Biased-100krad	503.29	477.42	-25.865
52	105	Biased-100krad	504.88	488.47	-16.41
53	105	Biased-100krad	502.33	486.53	-15.797
54	105	Biased-100krad	499.03	482.07	-16.965

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	499.32	501.62	504.91	2.9252	499.49	501.68	504.89	2.8394	-0.0255	0.057833	0.1709	0.10152
30	498.62	501.6	506.11	2.9673	497.26	501.89	508.49	4.2367	-1.6175	0.2928	2.3772	1.7172
35	500.28	503.74	507.92	3.513	489.94	497.76	502.81	5.0174	-10.333	-5.9775	-3.9169	2.6241
50	499.94	503.62	509.7	3.7052	498.21	503.49	510.44	4.8418	-1.836	-0.13286	1.8359	1.6047
55	502.91	504	504.96	0.84521	488.14	492.59	494.19	2.5266	-16.825	-11.414	-8.7196	3.1589
100	501.86	504.35	506.95	1.8533	500.08	503.58	509.4	3.7506	-3.1493	-0.77882	2.4458	2.081
105	499.03	502.4	504.88	2.138	477.42	484.31	488.47	4.5371	-25.865	-18.091	-15.418	4.3856

Device Test: 33.6 _Enable|FallingThreshold/EN2/3/3///90.9/634//0///@EN_VTH_FALLING





Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

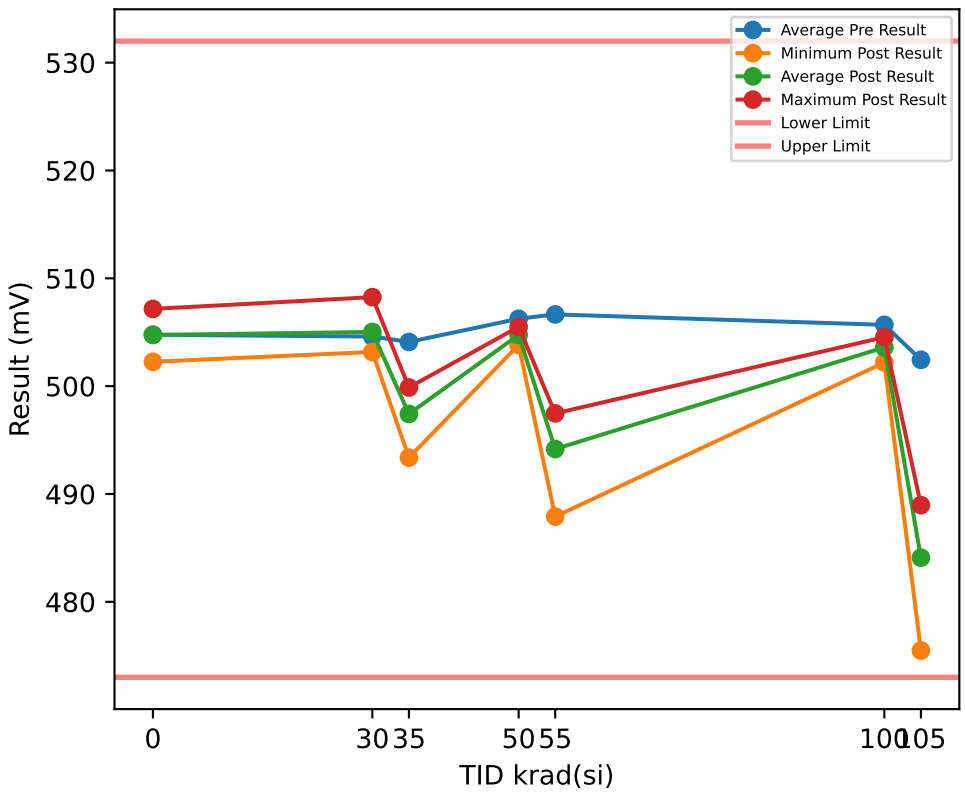
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	500.5	500.52	0.025
2	0	CU2	505.09	505.06	-0.0272
3	0	CU3	499.21	499.43	0.2172
11	30	Unbiased-30krad	501.97	502.99	1.0191
12	30	Unbiased-30krad	506.18	508.54	2.3631
13	30	Unbiased-30krad	499.14	500.14	0.992
14	30	Unbiased-30krad	501.76	500.12	-1.6371
15	30	Unbiased-30krad	498.55	497.18	-1.3665
16	35	Biased-30krad	501.24	497.33	-3.9112
17	35	Biased-30krad	500.14	489.77	-10.371
18	35	Biased-30krad	508.11	501.53	-6.582
19	35	Biased-30krad	507.2	502.97	-4.2341
20	35	Biased-30krad	502.04	497.15	-4.8958
30	50	Unbiased-50krad	509.84	510.47	0.634
31	50	Unbiased-50krad	504.13	506.1	1.9714
32	50	Unbiased-50krad	501.84	500	-1.8401
33	50	Unbiased-50krad	499.88	498.26	-1.6263
34	50	Unbiased-50krad	502.38	502.8	0.4188
40	55	Biased-50krad	504.5	493.37	-11.131
41	55	Biased-50krad	505.13	488.26	-16.866
42	55	Biased-50krad	502.74	494.02	-8.7122
43	55	Biased-50krad	503.37	493.03	-10.338
44	55	Biased-50krad	504.2	494.13	-10.071
45	100	Unbiased-100krad	504.72	504.33	-0.3845
46	100	Unbiased-100krad	507.14	509.45	2.3136
47	100	Unbiased-100krad	503.74	500.52	-3.2201
48	100	Unbiased-100krad	501.69	499.86	-1.8249
49	100	Unbiased-100krad	504.6	503.51	-1.0834
50	105	Biased-100krad	502.54	486.88	-15.661
51	105	Biased-100krad	503.34	477.46	-25.889
52	105	Biased-100krad	505.05	488.53	-16.52
53	105	Biased-100krad	502.38	486.47	-15.915
54	105	Biased-100krad	499.18	482.19	-16.991

Test Statistics (mV)

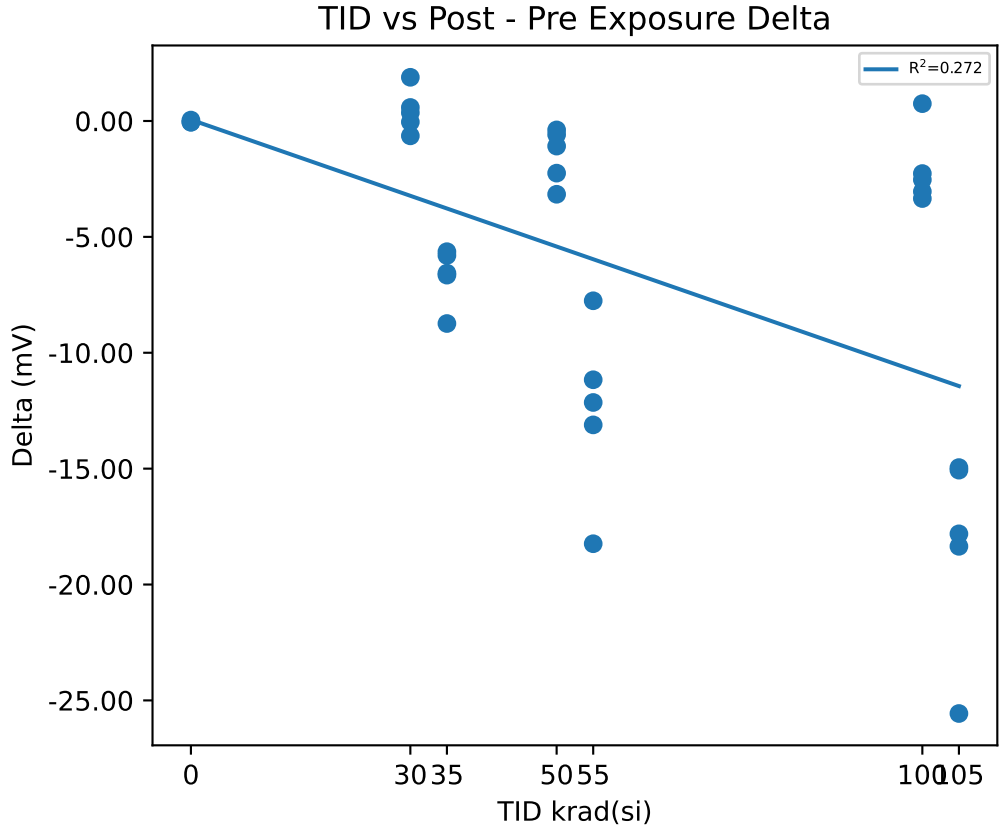
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	499.21	501.6	505.09	3.0901	499.43	501.67	505.06	2.9874	-0.0272	0.071667	0.2172	0.12871
30	498.55	501.52	506.18	3.0182	497.18	501.79	508.54	4.2944	-1.6371	0.27412	2.3631	1.716
35	500.14	503.75	508.11	3.6473	489.77	497.75	502.97	5.1419	-10.371	-5.9989	-3.9112	2.6528
50	499.88	503.61	509.84	3.7953	498.26	503.52	510.47	4.8901	-1.8401	-0.08844	1.9714	1.6167
55	502.74	503.99	505.13	0.94232	488.26	492.56	494.13	2.4486	-16.866	-11.424	-8.7122	3.1648
100	501.69	504.38	507.14	1.9635	499.86	503.54	509.45	3.8149	-3.2201	-0.83986	2.3136	2.0522
105	499.18	502.5	505.05	2.1375	477.46	484.3	488.53	4.4877	-25.889	-18.195	-15.661	4.3323

Device Test: 33.7 _Enable|FallingThreshold/EN3/3/3///90.9/634//0///@EN_VTH_FALLING

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

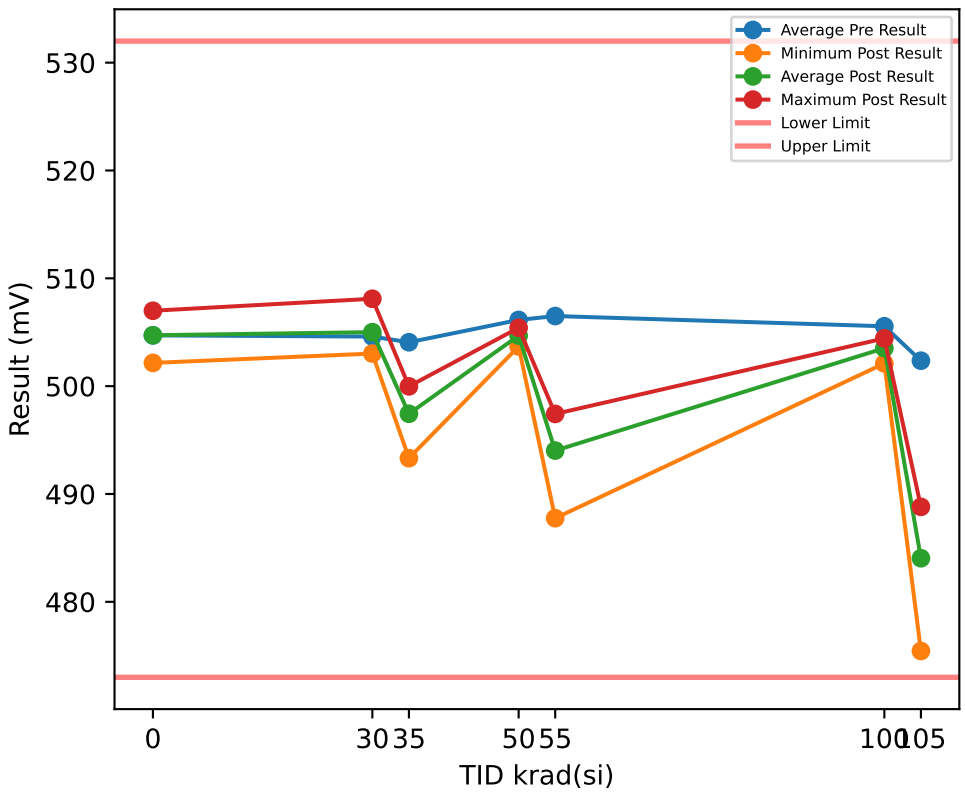
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	502.31	502.26	-0.0447
2	0	CU2	504.87	504.82	-0.0556
3	0	CU3	507.12	507.16	0.0396
11	30	Unbiased-30krad	503.48	504.06	0.5837
12	30	Unbiased-30krad	503.21	503.17	-0.0427
13	30	Unbiased-30krad	502.76	504.64	1.8856
14	30	Unbiased-30krad	505.65	505.01	-0.6412
15	30	Unbiased-30krad	507.9	508.25	0.3576
16	35	Biased-30krad	505.68	499.88	-5.8008
17	35	Biased-30krad	502.11	493.38	-8.7382
18	35	Biased-30krad	505.98	499.42	-6.5658
19	35	Biased-30krad	503.84	497.19	-6.6509
20	35	Biased-30krad	502.89	497.25	-5.6391
30	50	Unbiased-50krad	504.75	504.37	-0.3847
31	50	Unbiased-50krad	507.9	504.74	-3.1617
32	50	Unbiased-50krad	505.94	505.35	-0.5876
33	50	Unbiased-50krad	506.59	505.5	-1.0836
34	50	Unbiased-50krad	506.08	503.83	-2.25
40	55	Biased-50krad	507.34	495.19	-12.145
41	55	Biased-50krad	506.15	487.91	-18.24
42	55	Biased-50krad	505.22	494.05	-11.165
43	55	Biased-50krad	509.33	496.22	-13.112
44	55	Biased-50krad	505.23	497.47	-7.7569
45	100	Unbiased-100krad	507.8	504.45	-3.346
46	100	Unbiased-100krad	504.46	502.19	-2.2674
47	100	Unbiased-100krad	505.4	502.35	-3.0441
48	100	Unbiased-100krad	506.98	504.45	-2.5353
49	100	Unbiased-100krad	503.79	504.54	0.7482
50	105	Biased-100krad	504.03	488.97	-15.065
51	105	Biased-100krad	501.05	475.48	-25.565
52	105	Biased-100krad	501.8	486.85	-14.954
53	105	Biased-100krad	499.74	481.93	-17.813
54	105	Biased-100krad	505.59	487.24	-18.352

Test Statistics (mV)

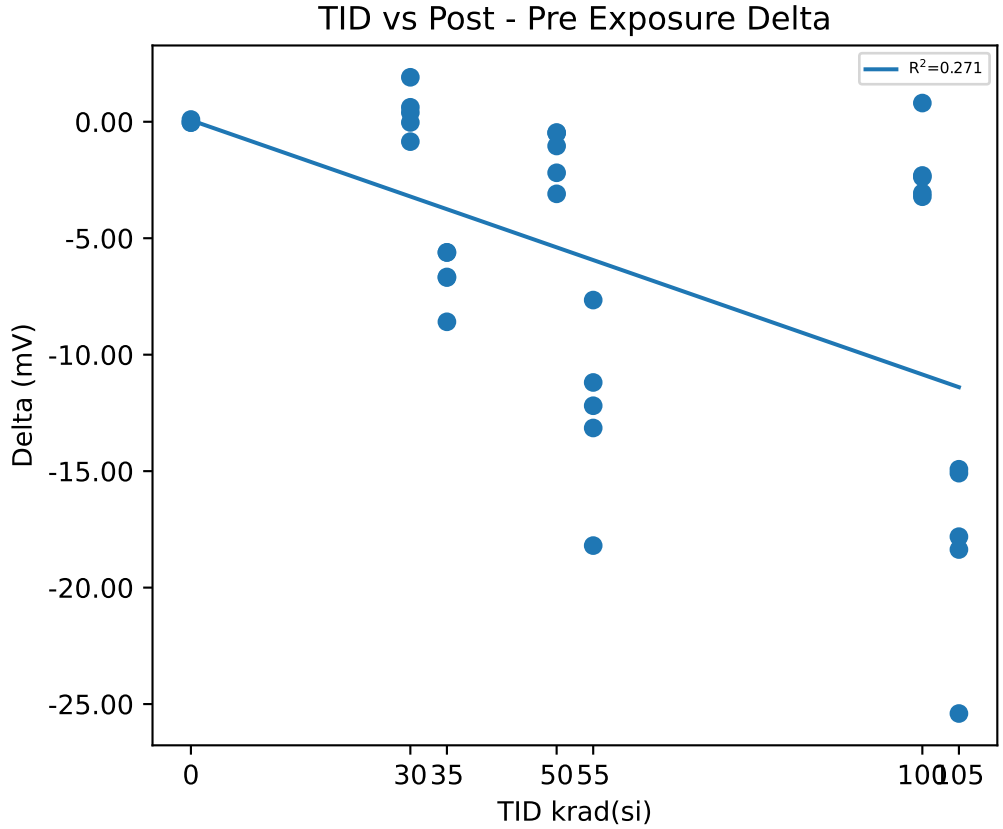
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	502.31	504.77	507.12	2.4101	502.26	504.75	507.16	2.4513	-0.0556	-0.020233	0.0396	0.052103
30	502.76	504.6	507.9	2.1524	503.17	505.03	508.25	1.9318	-0.6412	0.4286	1.8856	0.93789
35	502.11	504.1	505.98	1.6967	493.38	497.42	499.88	2.572	-8.7382	-6.679	-5.6391	1.2356
50	504.75	506.25	507.9	1.1426	503.83	504.76	505.5	0.69364	-3.1617	-1.4935	-0.3847	1.1804
55	505.22	506.65	509.33	1.7306	487.91	494.17	497.47	3.7218	-18.24	-12.484	-7.7569	3.7988
100	503.79	505.69	507.8	1.6812	502.19	503.6	504.54	1.211	-3.346	-2.0889	0.7482	1.6411
105	499.74	502.44	505.59	2.3505	475.48	484.09	488.97	5.4791	-25.565	-18.35	-14.954	4.3205

Device Test: 33.8 _Enable|FallingThreshold/EN4/3/3///90.9/634//0///@EN_VTH_FALLING

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

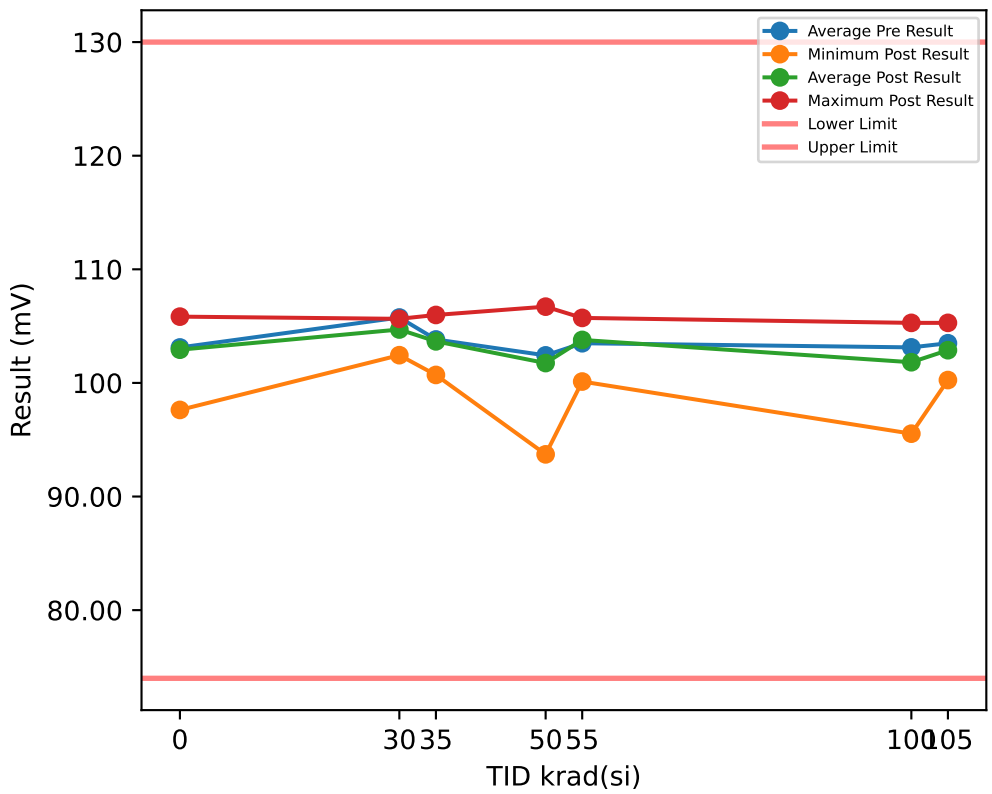
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	502.19	502.16	-0.0315
2	0	CU2	505.05	505.01	-0.036
3	0	CU3	506.9	506.99	0.0971
11	30	Unbiased-30krad	503.59	504.21	0.6213
12	30	Unbiased-30krad	503.05	503.02	-0.0288
13	30	Unbiased-30krad	502.89	504.8	1.9093
14	30	Unbiased-30krad	505.76	504.9	-0.8532
15	30	Unbiased-30krad	507.71	508.1	0.396
16	35	Biased-30krad	505.59	499.98	-5.6052
17	35	Biased-30krad	501.91	493.32	-8.5882
18	35	Biased-30krad	506.14	499.47	-6.663
19	35	Biased-30krad	504.01	497.32	-6.6888
20	35	Biased-30krad	502.71	497.1	-5.6138
30	50	Unbiased-50krad	504.91	504.42	-0.4882
31	50	Unbiased-50krad	507.72	504.63	-3.0944
32	50	Unbiased-50krad	505.74	505.28	-0.4606
33	50	Unbiased-50krad	506.45	505.41	-1.0402
34	50	Unbiased-50krad	505.87	503.68	-2.1905
40	55	Biased-50krad	507.23	495.03	-12.191
41	55	Biased-50krad	505.95	487.75	-18.196
42	55	Biased-50krad	505.06	493.87	-11.192
43	55	Biased-50krad	509.2	496.05	-13.147
44	55	Biased-50krad	505.08	497.42	-7.6551
45	100	Unbiased-100krad	507.62	504.4	-3.2182
46	100	Unbiased-100krad	504.41	502.11	-2.3054
47	100	Unbiased-100krad	505.34	502.28	-3.0586
48	100	Unbiased-100krad	506.77	504.39	-2.3751
49	100	Unbiased-100krad	503.63	504.43	0.8033
50	105	Biased-100krad	503.89	488.81	-15.087
51	105	Biased-100krad	500.84	475.44	-25.405
52	105	Biased-100krad	501.96	487.04	-14.918
53	105	Biased-100krad	499.65	481.84	-17.812
54	105	Biased-100krad	505.46	487.09	-18.365

Test Statistics (mV)

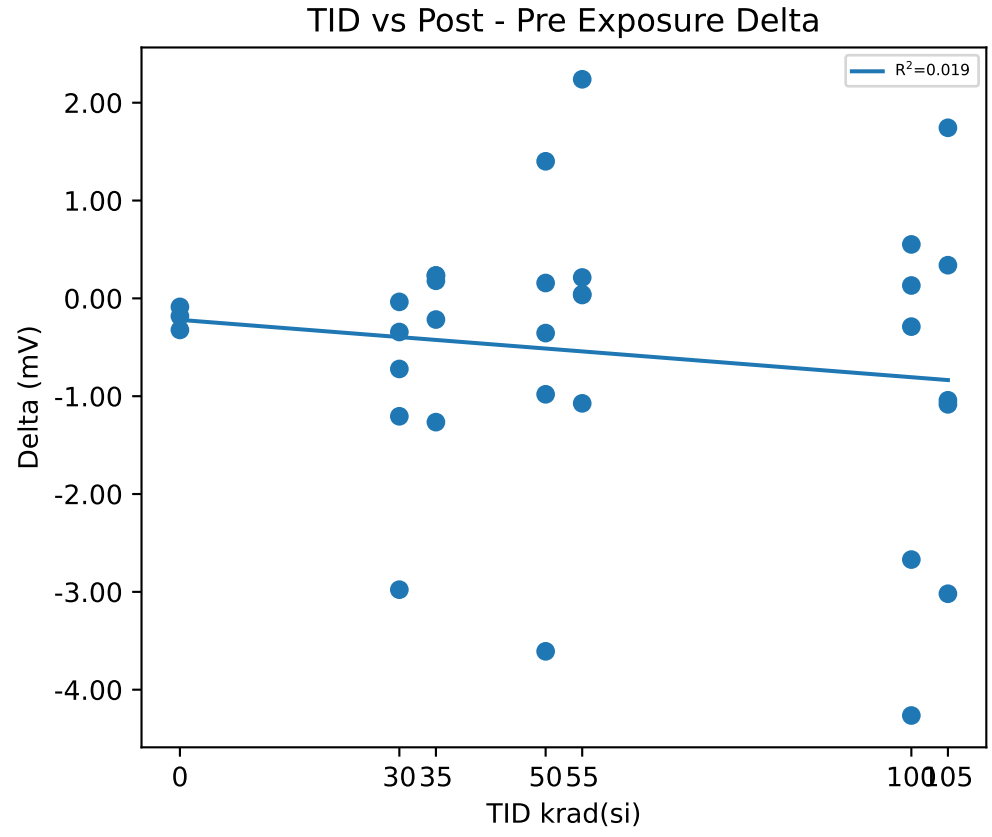
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	502.19	504.71	506.9	2.3723	502.16	504.72	506.99	2.4316	-0.036	0.0098667	0.0971	0.07558
30	502.89	504.6	507.71	2.0828	503.02	505.01	508.1	1.8855	-0.8532	0.40892	1.9093	1.0101
35	501.91	504.07	506.14	1.8089	493.32	497.44	499.98	2.6309	-8.5882	-6.6318	-5.6052	1.2168
50	504.91	506.14	507.72	1.0414	503.68	504.69	505.41	0.70172	-3.0944	-1.4548	-0.4606	1.1537
55	505.06	506.5	509.2	1.7463	487.75	494.03	497.42	3.7429	-18.196	-12.476	-7.6551	3.8123
100	503.63	505.55	507.62	1.6429	502.11	503.52	504.43	1.2144	-3.2182	-2.0308	0.8033	1.635
105	499.65	502.36	505.46	2.332	475.44	484.04	488.81	5.4743	-25.405	-18.318	-14.918	4.2568

Device Test: 33.9 _Enable|Hys/EN1/3/3///90.9/634//0///@EN_VTH_HYST

TID vs Result Stats



TID vs Post - Pre Exposure Delta



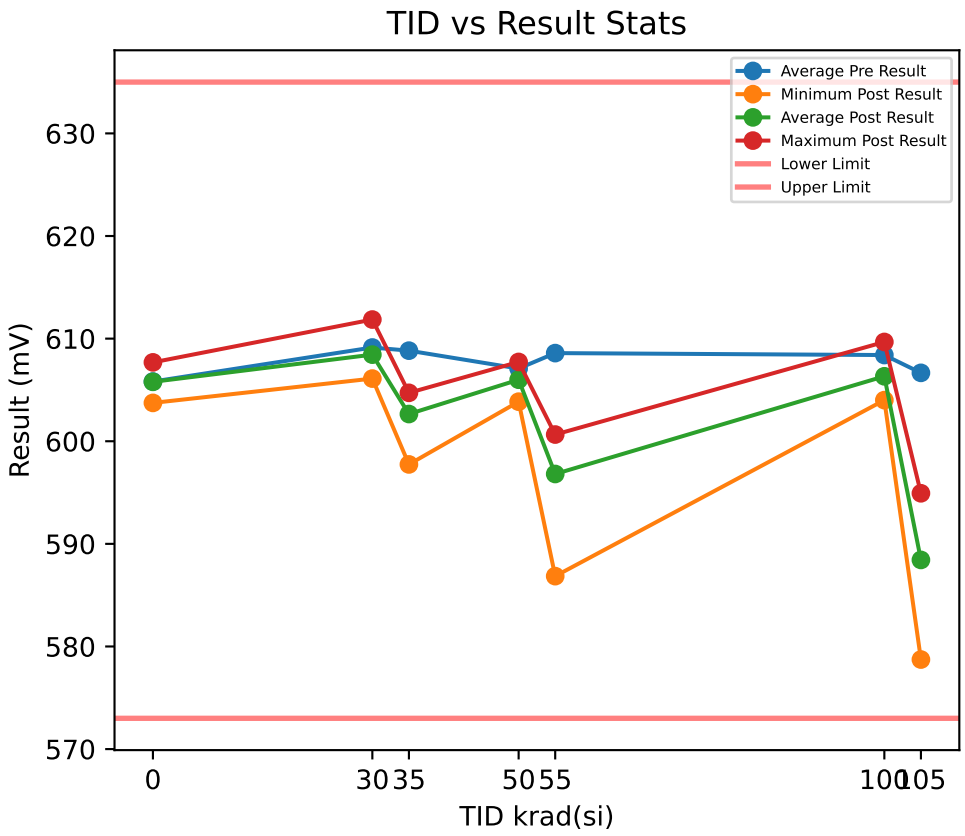
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

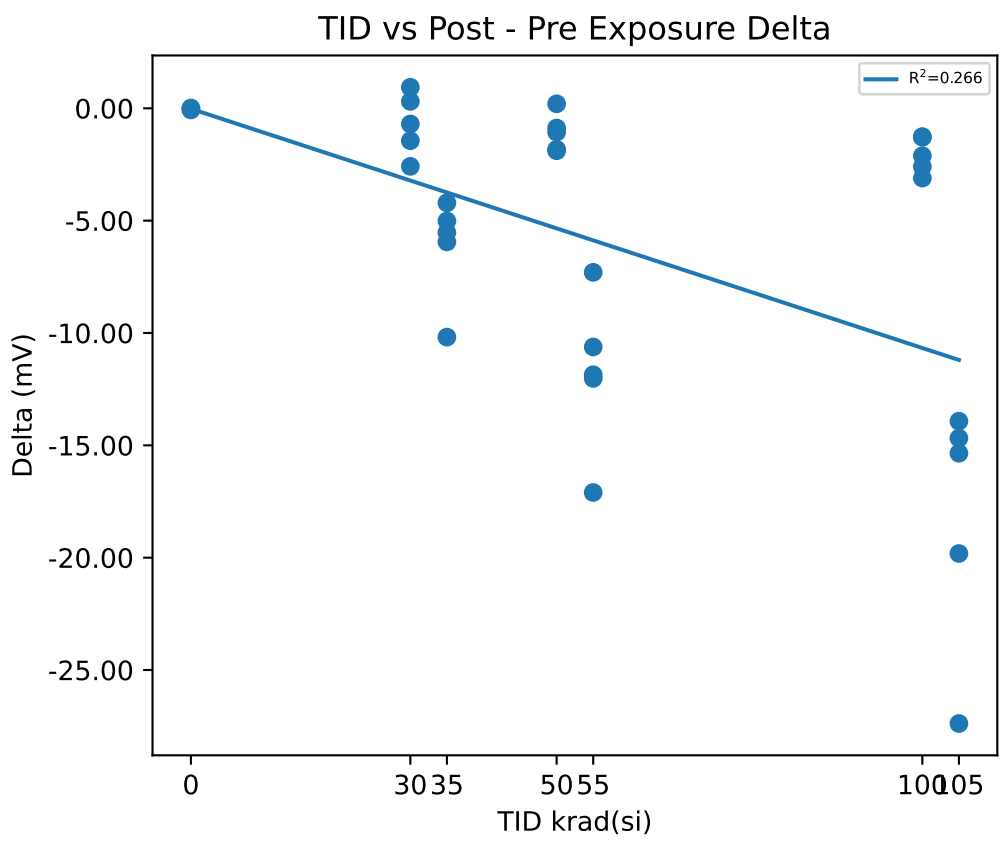
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	105.5	105.31	-0.1817
2	0	CU2	97.945	97.623	-0.3225
3	0	CU3	105.92	105.83	-0.087
11	30	Unbiased-30krad	104.89	104.86	-0.0358
12	30	Unbiased-30krad	105.42	102.44	-2.9776
13	30	Unbiased-30krad	106.36	105.64	-0.7215
14	30	Unbiased-30krad	105.94	105.6	-0.3438
15	30	Unbiased-30krad	106.17	104.97	-1.2053
16	35	Biased-30krad	105.11	104.89	-0.2164
17	35	Biased-30krad	105.17	105.4	0.2342
18	35	Biased-30krad	101.13	101.31	0.1798
19	35	Biased-30krad	101.97	100.7	-1.265
20	35	Biased-30krad	105.75	105.98	0.2329
30	50	Unbiased-50krad	94.066	93.712	-0.3548
31	50	Unbiased-50krad	105.14	101.53	-3.6078
32	50	Unbiased-50krad	105.61	105.76	0.1571
33	50	Unbiased-50krad	105.31	106.71	1.4012
34	50	Unbiased-50krad	102.01	101.03	-0.9806
40	55	Biased-50krad	103.77	103.8	0.0344
41	55	Biased-50krad	99.908	100.12	0.2137
42	55	Biased-50krad	105.68	105.72	0.0423
43	55	Biased-50krad	105.57	104.49	-1.073
44	55	Biased-50krad	102.54	104.78	2.2394
45	100	Unbiased-100krad	103.38	100.71	-2.6699
46	100	Unbiased-100krad	99.796	95.533	-4.2638
47	100	Unbiased-100krad	102.71	103.26	0.5515
48	100	Unbiased-100krad	104.61	104.32	-0.2888
49	100	Unbiased-100krad	105.15	105.29	0.1317
50	105	Biased-100krad	106.37	105.29	-1.0832
51	105	Biased-100krad	101.29	100.25	-1.0417
52	105	Biased-100krad	102.11	103.85	1.7435
53	105	Biased-100krad	103.41	103.75	0.3391
54	105	Biased-100krad	104.27	101.25	-3.0191

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.945	103.12	105.92	4.4876	97.623	102.92	105.83	4.5985	-0.3225	-0.19707	-0.087	0.1185
30	104.89	105.76	106.36	0.59847	102.44	104.7	105.64	1.3124	-2.9776	-1.0568	-0.0358	1.1592
35	101.13	103.82	105.75	2.1132	100.7	103.66	105.98	2.4603	-1.265	-0.1669	0.2342	0.64211
50	94.066	102.42	105.61	4.8947	93.712	101.75	106.71	5.1459	-3.6078	-0.67698	1.4012	1.8574
55	99.908	103.49	105.68	2.3945	100.12	103.78	105.72	2.1602	-1.073	0.29136	2.2394	1.2032
100	99.796	103.13	105.15	2.099	95.533	101.82	105.29	3.9077	-4.2638	-1.3079	0.5515	2.0713
105	101.29	103.49	106.37	1.9771	100.25	102.88	105.29	2.0648	-3.0191	-0.61228	1.7435	1.7786

Device Test: 34.1 _Enable|RisingThreshold/EN1/7/7///90.9/634//0///@EN_VTH_RISING





Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

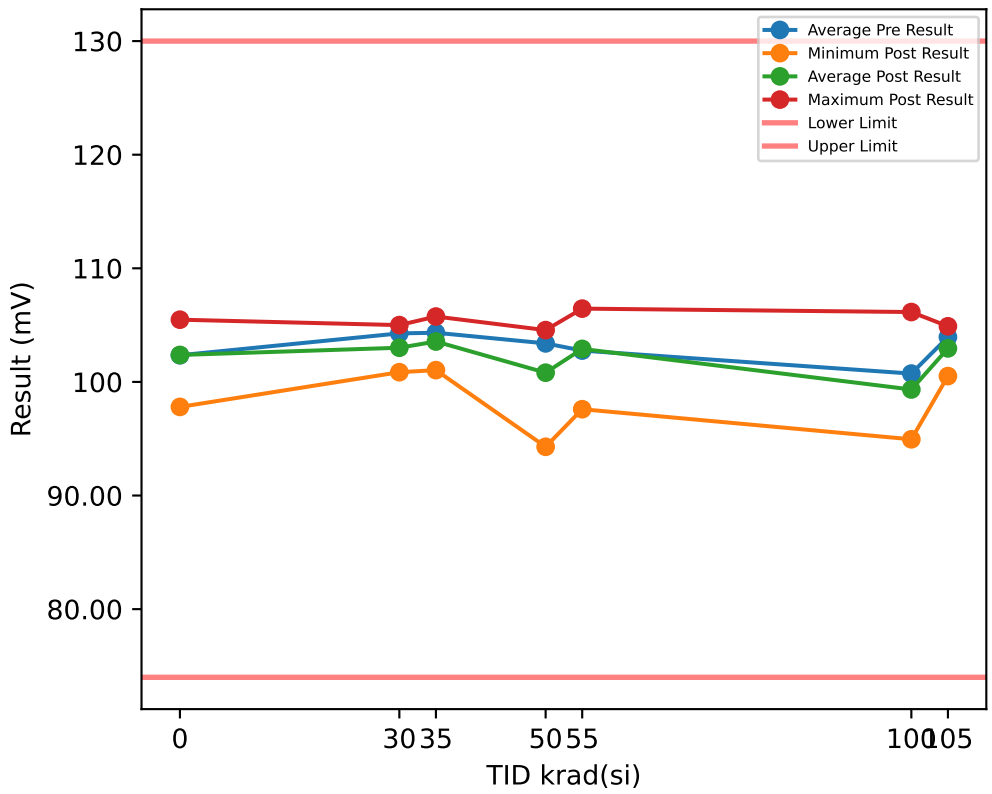
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	607.76	607.69	-0.072
2	0	CU2	603.72	603.74	0.014
3	0	CU3	605.97	605.95	-0.0267
11	30	Unbiased-30krad	608.61	609.55	0.9356
12	30	Unbiased-30krad	612.56	611.86	-0.6973
13	30	Unbiased-30krad	607.44	607.75	0.3084
14	30	Unbiased-30krad	609.51	606.92	-2.5843
15	30	Unbiased-30krad	607.55	606.11	-1.4421
16	35	Biased-30krad	606.89	602.68	-4.2074
17	35	Biased-30krad	607.92	597.74	-10.183
18	35	Biased-30krad	610.66	604.72	-5.9458
19	35	Biased-30krad	609.76	604.23	-5.5315
20	35	Biased-30krad	608.9	603.89	-5.0137
30	50	Unbiased-50krad	605.64	605.84	0.2007
31	50	Unbiased-50krad	609.62	607.73	-1.8891
32	50	Unbiased-50krad	609.49	607.66	-1.8242
33	50	Unbiased-50krad	604.91	603.86	-1.0595
34	50	Unbiased-50krad	605.76	604.89	-0.8774
40	55	Biased-50krad	609.65	597.79	-11.858
41	55	Biased-50krad	603.95	586.85	-17.099
42	55	Biased-50krad	610.81	598.79	-12.022
43	55	Biased-50krad	610.58	599.96	-10.622
44	55	Biased-50krad	607.95	600.65	-7.3002
45	100	Unbiased-100krad	609.74	606.63	-3.105
46	100	Unbiased-100krad	606.85	605.56	-1.2882
47	100	Unbiased-100krad	606.6	604.01	-2.5937
48	100	Unbiased-100krad	607.88	605.77	-2.1139
49	100	Unbiased-100krad	610.93	609.68	-1.2582
50	105	Biased-100krad	608.85	594.93	-13.926
51	105	Biased-100krad	606.11	578.73	-27.381
52	105	Biased-100krad	607.95	592.6	-15.352
53	105	Biased-100krad	606.69	592.01	-14.679
54	105	Biased-100krad	603.72	583.9	-19.814

Test Statistics (mV)

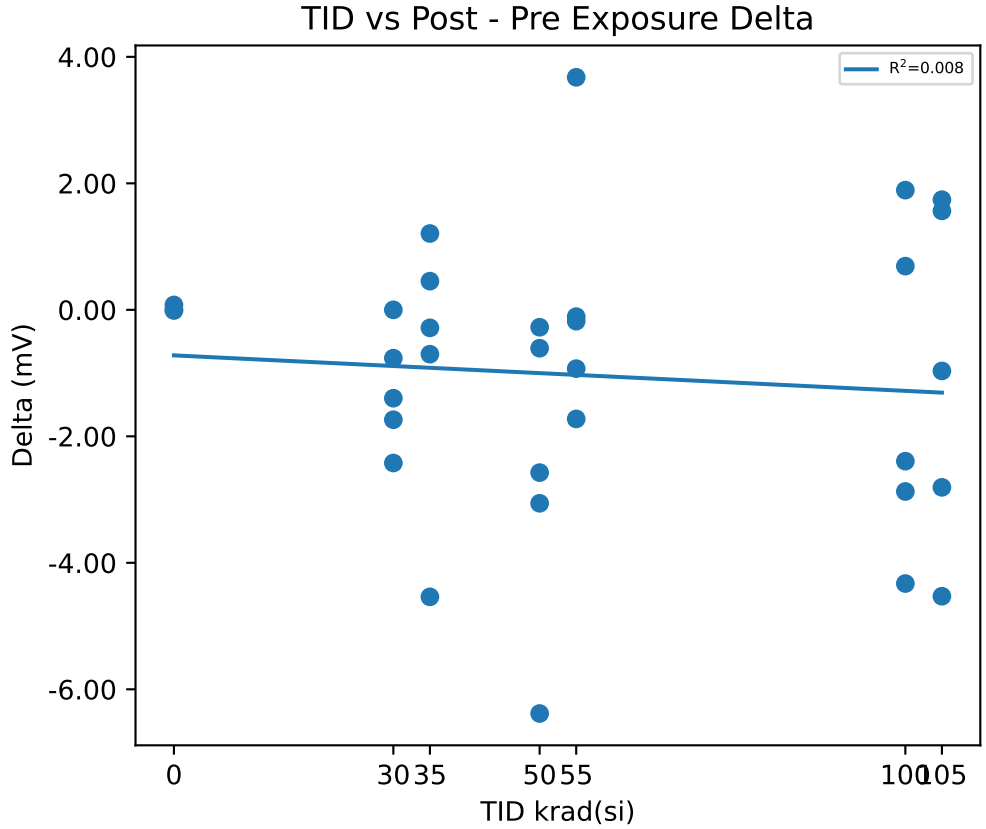
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	603.72	605.82	607.76	2.0223	603.74	605.79	607.69	1.9795	-0.072	-0.028233	0.014	0.04302
30	607.44	609.13	612.56	2.0915	606.11	608.44	611.86	2.2992	-2.5843	-0.69594	0.9356	1.3958
35	606.89	608.83	610.66	1.4837	597.74	602.65	604.72	2.8453	-10.183	-6.1763	-4.2074	2.3318
50	604.91	607.09	609.62	2.2763	603.86	606	607.73	1.7045	-1.8891	-1.0899	0.2007	0.84995
55	603.95	608.59	610.81	2.8254	586.85	596.81	600.65	5.6722	-17.099	-11.78	-7.3002	3.5272
100	606.6	608.4	610.93	1.8787	604.01	606.33	609.68	2.0967	-3.105	-2.0718	-1.2582	0.80895
105	603.72	606.66	608.85	1.9654	578.73	588.43	594.93	6.839	-27.381	-18.23	-13.926	5.6051

Device Test: 34.10 _Enable|Hys/EN2/7/7///90.9/634//0///@EN_VTH_HYST

TID vs Result Stats



TID vs Post - Pre Exposure Delta



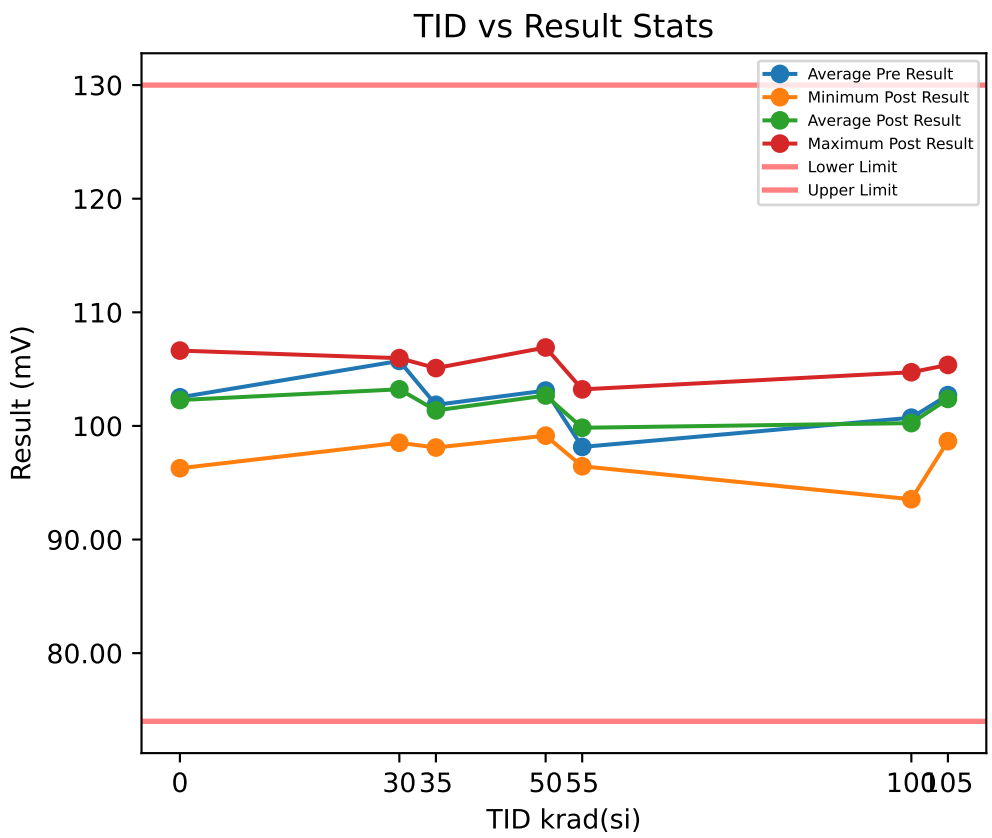
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

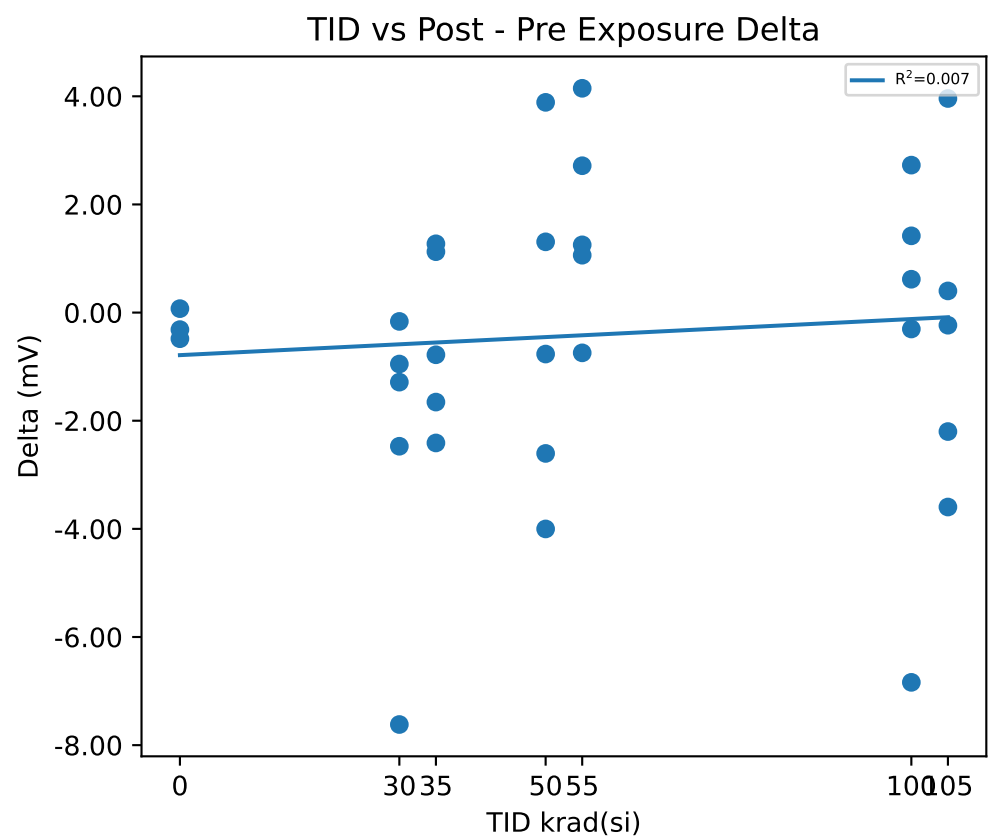
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.84	103.84	0.001
2	0	CU2	97.723	97.8	0.0774
3	0	CU3	105.49	105.48	-0.0107
11	30	Unbiased-30krad	102.25	100.86	-1.3974
12	30	Unbiased-30krad	104.73	102.31	-2.4219
13	30	Unbiased-30krad	104.69	102.95	-1.7376
14	30	Unbiased-30krad	104.69	103.92	-0.7643
15	30	Unbiased-30krad	105	105	-0.0004
16	35	Biased-30krad	103.84	103.56	-0.2848
17	35	Biased-30krad	100.9	102.1	1.2068
18	35	Biased-30krad	105.58	101.04	-4.5382
19	35	Biased-30krad	105.3	105.76	0.4537
20	35	Biased-30krad	106.02	105.32	-0.7016
30	50	Unbiased-50krad	94.896	94.29	-0.6069
31	50	Unbiased-50krad	103.38	100.32	-3.0589
32	50	Unbiased-50krad	104.7	104.42	-0.2754
33	50	Unbiased-50krad	107.13	104.56	-2.5739
34	50	Unbiased-50krad	106.86	100.48	-6.3827
40	55	Biased-50krad	104.27	102.54	-1.725
41	55	Biased-50krad	97.705	97.598	-0.1074
42	55	Biased-50krad	104.28	103.35	-0.9302
43	55	Biased-50krad	104.77	104.59	-0.1798
44	55	Biased-50krad	102.77	106.45	3.6768
45	100	Unbiased-100krad	104.26	106.15	1.8924
46	100	Unbiased-100krad	97.823	94.95	-2.8724
47	100	Unbiased-100krad	102.09	102.79	0.6912
48	100	Unbiased-100krad	100.45	96.122	-4.3276
49	100	Unbiased-100krad	99.046	96.653	-2.393
50	105	Biased-100krad	105.55	104.58	-0.9662
51	105	Biased-100krad	106.7	102.17	-4.5283
52	105	Biased-100krad	101.03	102.59	1.5643
53	105	Biased-100krad	103.15	104.9	1.7412
54	105	Biased-100krad	103.32	100.51	-2.8067

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.723	102.35	105.49	4.0906	97.8	102.37	105.48	4.0429	-0.0107	0.022567	0.0774	0.047846
30	102.25	104.27	105	1.1368	100.86	103.01	105	1.5758	-2.4219	-1.2643	-0.0004	0.92591
35	100.9	104.33	106.02	2.0852	101.04	103.55	105.76	2.0254	-4.5382	-0.77282	1.2068	2.2274
50	94.896	103.39	107.13	4.9973	94.29	100.81	104.56	4.1824	-6.3827	-2.5796	-0.2754	2.4441
55	97.705	102.76	104.77	2.9228	97.598	102.91	106.45	3.3132	-1.725	0.14688	3.6768	2.0794
100	97.823	100.73	104.26	2.5339	94.95	99.332	106.15	4.8763	-4.3276	-1.4019	1.8924	2.5951
105	101.03	103.95	106.7	2.2178	100.51	102.95	104.9	1.8115	-4.5283	-0.99914	1.7412	2.7297

Device Test: 34.11 _Enable|Hys/EN3/7/7///90.9/634//0///@EN_VTH_HYST





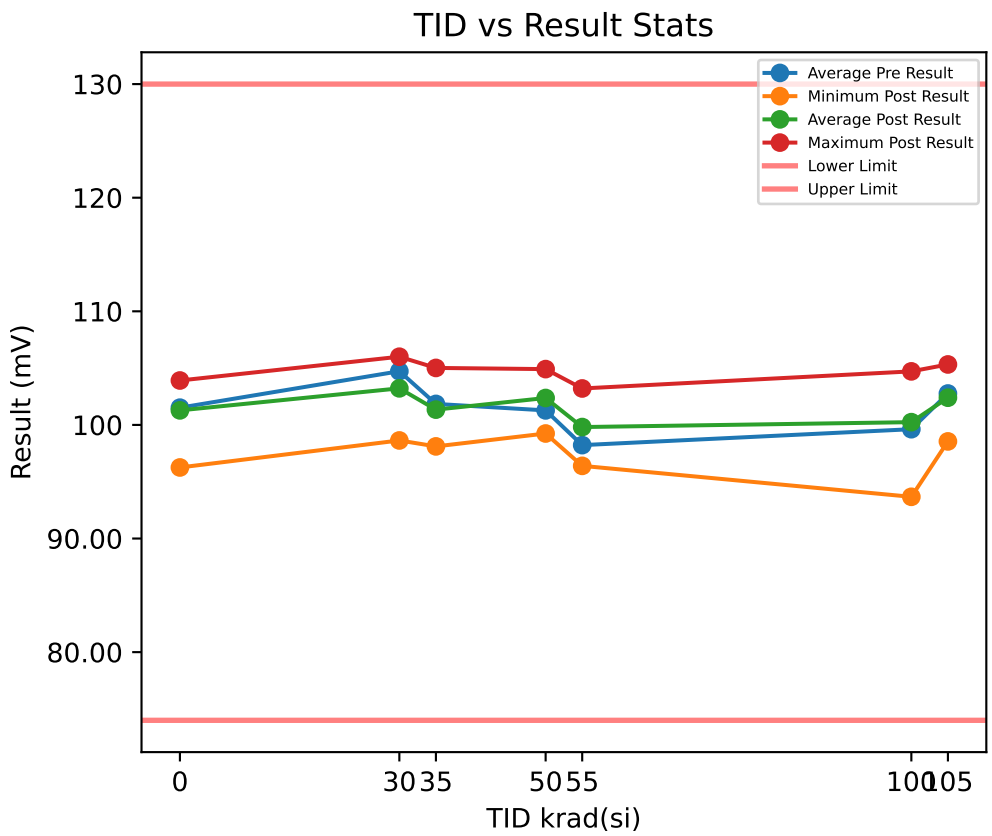
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

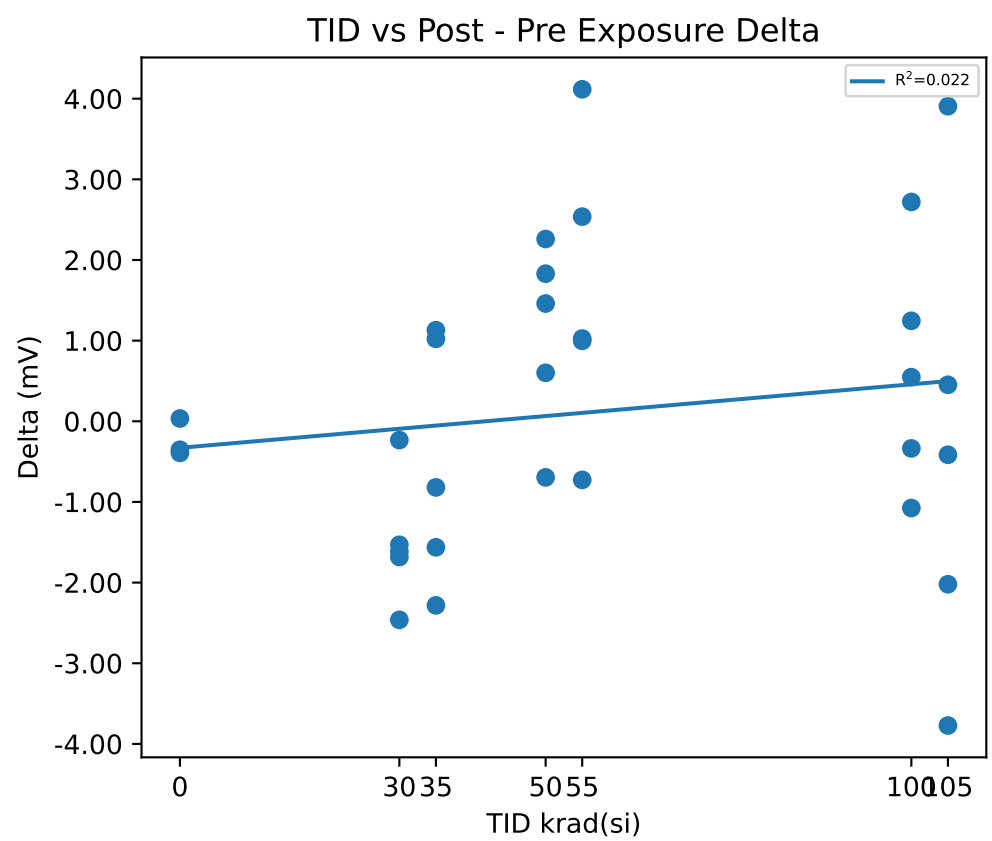
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	107.11	106.63	-0.4831
2	0	CU2	104.24	103.93	-0.3149
3	0	CU3	96.202	96.275	0.0731
11	30	Unbiased-30krad	106.39	105.11	-1.2864
12	30	Unbiased-30krad	102.31	102.15	-0.1634
13	30	Unbiased-30krad	106.92	105.96	-0.9515
14	30	Unbiased-30krad	106.85	104.37	-2.472
15	30	Unbiased-30krad	106.14	98.518	-7.6182
16	35	Biased-30krad	103.96	105.09	1.1262
17	35	Biased-30krad	104.9	102.49	-2.4111
18	35	Biased-30krad	99.383	100.66	1.2721
19	35	Biased-30krad	99.753	98.098	-1.6552
20	35	Biased-30krad	101.28	100.5	-0.7802
30	50	Unbiased-50krad	97.834	99.142	1.3084
31	50	Unbiased-50krad	103.02	106.9	3.8881
32	50	Unbiased-50krad	102.06	101.29	-0.7668
33	50	Unbiased-50krad	106.13	103.53	-2.6048
34	50	Unbiased-50krad	106.51	102.51	-4.0013
40	55	Biased-50krad	97.193	96.448	-0.7448
41	55	Biased-50krad	100.5	103.22	2.7161
42	55	Biased-50krad	99.808	101.06	1.2527
43	55	Biased-50krad	95.562	99.71	4.1481
44	55	Biased-50krad	97.692	98.753	1.0611
45	100	Unbiased-100krad	98.311	98.928	0.6168
46	100	Unbiased-100krad	105.03	104.72	-0.3034
47	100	Unbiased-100krad	103.29	104.71	1.4195
48	100	Unbiased-100krad	90.818	93.545	2.7272
49	100	Unbiased-100krad	106.17	99.33	-6.8385
50	105	Biased-100krad	107.04	104.84	-2.2002
51	105	Biased-100krad	101.41	105.37	3.9596
52	105	Biased-100krad	102.25	98.658	-3.596
53	105	Biased-100krad	102.58	102.35	-0.2336
54	105	Biased-100krad	100.26	100.66	0.4006

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	96.202	102.52	107.11	5.6556	96.275	102.28	106.63	5.3706	-0.4831	-0.24163	0.0731	0.28525
30	102.31	105.72	106.92	1.9331	98.518	103.22	105.96	2.9867	-7.6182	-2.4983	-0.1634	2.9802
35	99.383	101.85	104.9	2.4777	98.098	101.37	105.09	2.6008	-2.4111	-0.48964	1.2721	1.6469
50	97.834	103.11	106.51	3.5235	99.142	102.68	106.9	2.8734	-4.0013	-0.43528	3.8881	3.1331
55	95.562	98.151	100.5	2.0058	96.448	99.837	103.22	2.5292	-0.7448	1.6866	4.1481	1.8446
100	90.818	100.72	106.17	6.2989	93.545	100.25	104.72	4.6758	-6.8385	-0.47568	2.7272	3.7269
105	100.26	102.71	107.04	2.5822	98.658	102.38	105.37	2.8195	-3.596	-0.33392	3.9596	2.877

Device Test: 34.12 _Enable|Hys/EN4/7/7///90.9/634//0///@EN_VTH_HYST





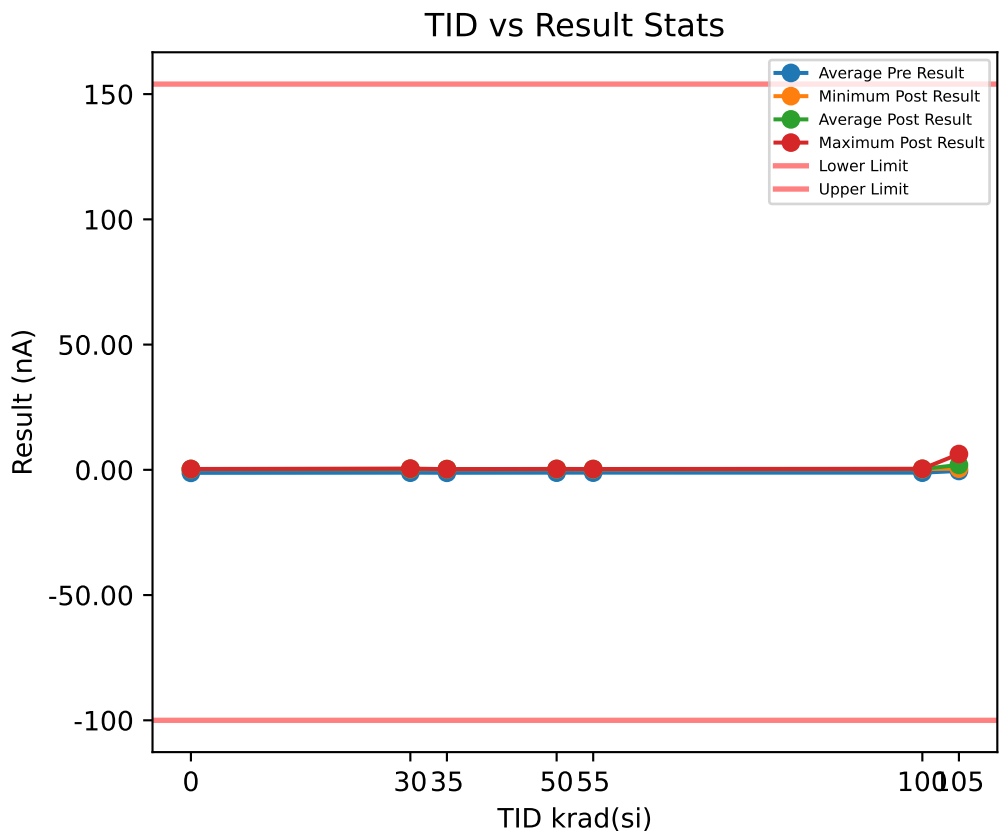
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

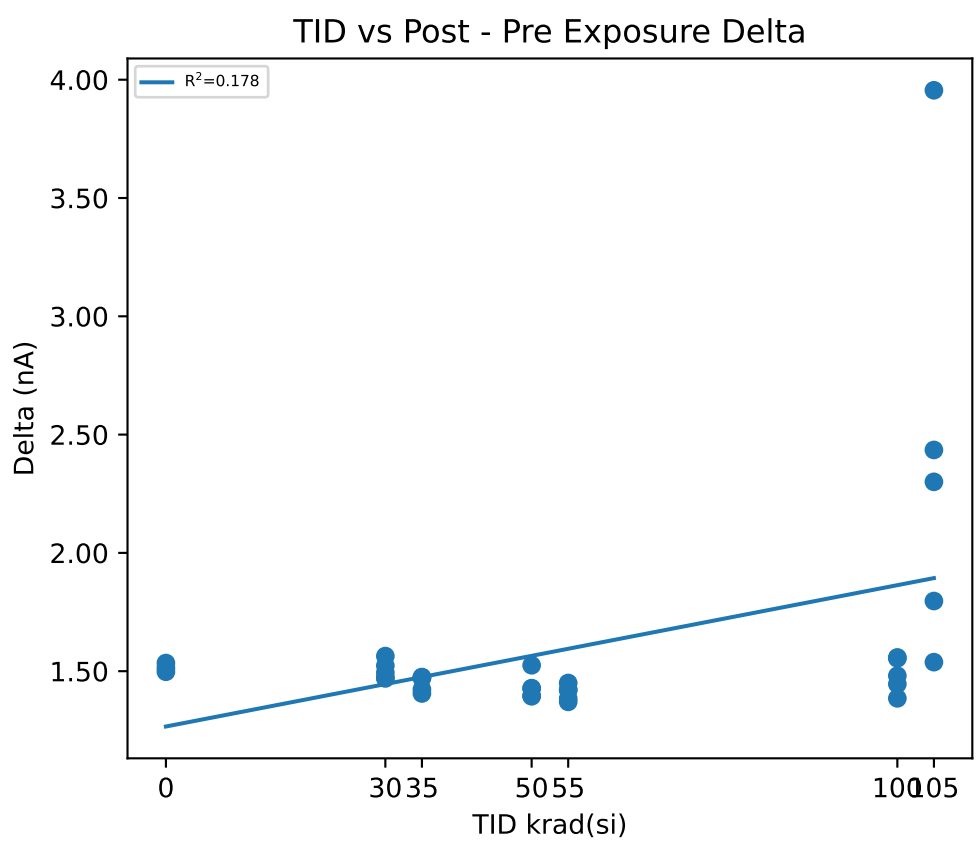
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	104.03	103.68	-0.3528
2	0	CU2	104.3	103.91	-0.3915
3	0	CU3	96.221	96.255	0.0345
11	30	Unbiased-30krad	106.7	105.01	-1.6829
12	30	Unbiased-30krad	102.3	102.07	-0.2332
13	30	Unbiased-30krad	107.53	106	-1.531
14	30	Unbiased-30krad	106.84	104.38	-2.4618
15	30	Unbiased-30krad	100.25	98.633	-1.615
16	35	Biased-30krad	103.99	105.02	1.0221
17	35	Biased-30krad	104.88	102.6	-2.2825
18	35	Biased-30krad	99.415	100.54	1.1291
19	35	Biased-30krad	99.672	98.11	-1.5623
20	35	Biased-30krad	101.28	100.46	-0.8197
30	50	Unbiased-50krad	97.784	99.245	1.4601
31	50	Unbiased-50krad	103.08	104.91	1.8303
32	50	Unbiased-50krad	102.08	101.39	-0.6953
33	50	Unbiased-50krad	101.36	103.62	2.2602
34	50	Unbiased-50krad	102.08	102.68	0.6014
40	55	Biased-50krad	97.123	96.397	-0.7263
41	55	Biased-50krad	100.67	103.21	2.5374
42	55	Biased-50krad	99.96	100.99	1.0261
43	55	Biased-50krad	95.604	99.72	4.1164
44	55	Biased-50krad	97.753	98.75	0.9972
45	100	Unbiased-100krad	98.403	98.951	0.5477
46	100	Unbiased-100krad	105.05	104.71	-0.3362
47	100	Unbiased-100krad	103.34	104.58	1.2459
48	100	Unbiased-100krad	90.953	93.672	2.7195
49	100	Unbiased-100krad	100.37	99.297	-1.0753
50	105	Biased-100krad	107.01	104.99	-2.0205
51	105	Biased-100krad	101.42	105.32	3.9069
52	105	Biased-100krad	102.32	98.549	-3.7719
53	105	Biased-100krad	102.74	102.33	-0.415
54	105	Biased-100krad	100.34	100.79	0.4526

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	96.221	101.52	104.3	4.589	96.255	101.28	103.91	4.3537	-0.3915	-0.2366	0.0345	0.23558
30	100.25	104.72	107.53	3.2467	98.633	103.22	106	2.944	-2.4618	-1.5048	-0.2332	0.80271
35	99.415	101.85	104.88	2.4904	98.11	101.35	105.02	2.596	-2.2825	-0.50266	1.1291	1.5312
50	97.784	101.28	103.08	2.0469	99.245	102.37	104.91	2.1717	-0.6953	1.0913	2.2602	1.1705
55	95.604	98.222	100.67	2.0798	96.397	99.812	103.21	2.5356	-0.7263	1.5902	4.1164	1.8245
100	90.953	99.623	105.05	5.4878	93.672	100.24	104.71	4.5978	-1.0753	0.62032	2.7195	1.4657
105	100.34	102.76	107.01	2.5439	98.549	102.4	105.32	2.8568	-3.7719	-0.36958	3.9069	2.8839

Device Test: 34.13 _Enable|LeakageHigh/EN1/7/7///90.9/634//0///@EN_LKG_CURR





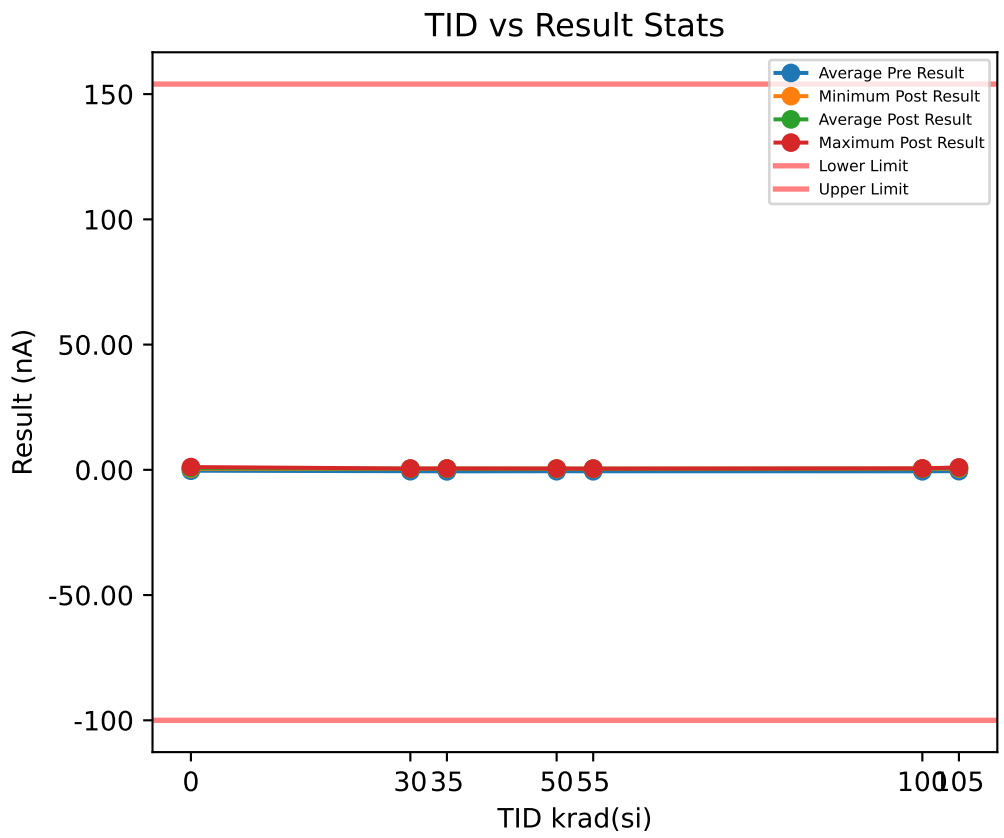
Test Results (Lower Limit = -100.0, Upper Limit = 154.0 (nA))

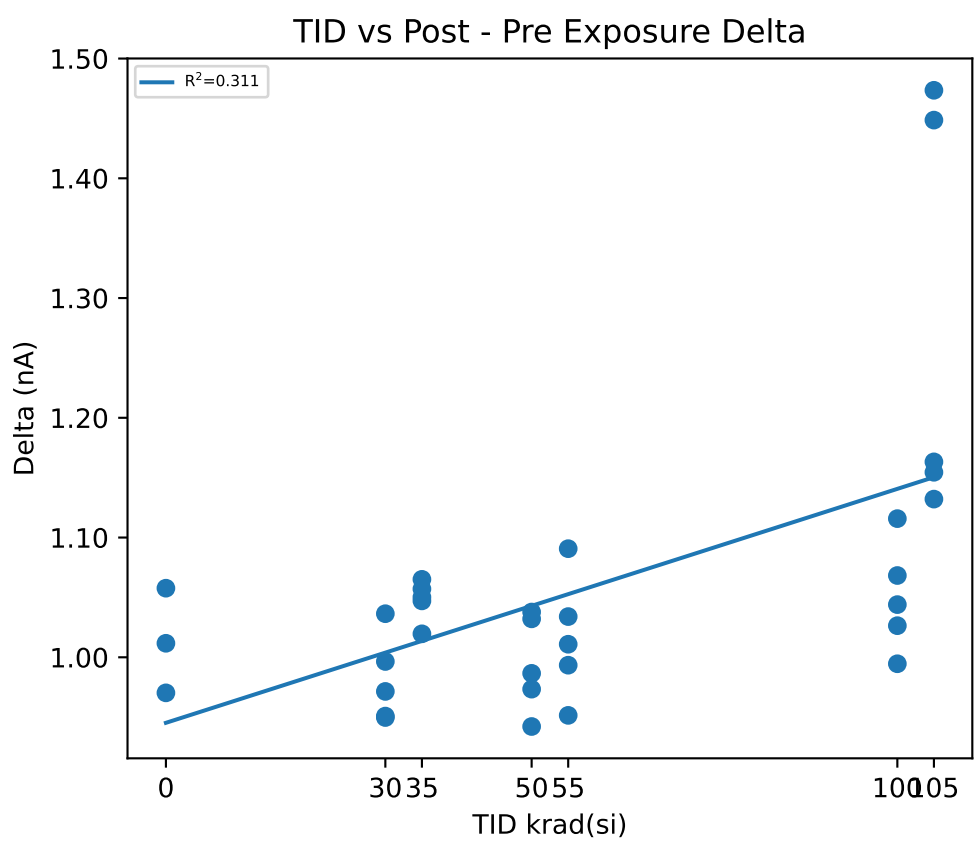
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-1.1703	0.3435	1.5138
2	0	CU2	-1.1878	0.3098	1.4976
3	0	CU3	-1.2677	0.2667	1.5344
11	30	Unbiased-30krad	-1.1154	0.3541	1.4695
12	30	Unbiased-30krad	-1.1591	0.4047	1.5638
13	30	Unbiased-30krad	-1.0355	0.4877	1.5232
14	30	Unbiased-30krad	-1.224	0.2698	1.4938
15	30	Unbiased-30krad	-1.1666	0.3067	1.4733
16	35	Biased-30krad	-1.2059	0.2649	1.4708
17	35	Biased-30krad	-1.2084	0.2655	1.4739
18	35	Biased-30krad	-1.2115	0.2636	1.4751
19	35	Biased-30krad	-1.1809	0.2424	1.4233
20	35	Biased-30krad	-1.116	0.2898	1.4058
30	50	Unbiased-50krad	-1.1478	0.2805	1.4283
31	50	Unbiased-50krad	-1.1578	0.3672	1.525
32	50	Unbiased-50krad	-1.1329	0.263	1.3959
33	50	Unbiased-50krad	-1.0898	0.3042	1.394
34	50	Unbiased-50krad	-1.1385	0.2879	1.4264
40	55	Biased-50krad	-1.0948	0.2755	1.3703
41	55	Biased-50krad	-1.0573	0.3273	1.3846
42	55	Biased-50krad	-1.1622	0.2879	1.4501
43	55	Biased-50krad	-1.2165	0.2037	1.4202
44	55	Biased-50krad	-1.1098	0.3123	1.4221
45	100	Unbiased-100krad	-1.1116	0.2736	1.3852
46	100	Unbiased-100krad	-1.1391	0.419	1.5581
47	100	Unbiased-100krad	-1.1603	0.2854	1.4457
48	100	Unbiased-100krad	-1.1079	0.3728	1.4807
49	100	Unbiased-100krad	-1.1528	0.4015	1.5543
50	105	Biased-100krad	-1.0586	0.4796	1.5382
51	105	Biased-100krad	2.3505	6.3058	3.9553
52	105	Biased-100krad	-1.2234	1.0769	2.3003
53	105	Biased-100krad	-1.1591	1.276	2.4351
54	105	Biased-100krad	-1.1922	0.6044	1.7966

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-1.2677	-1.2086	-1.1703	0.051925	0.2667	0.30667	0.3435	0.038496	1.4976	1.5153	1.5344	0.018444
30	-1.224	-1.1401	-1.0355	0.070096	0.2698	0.3646	0.4877	0.085457	1.4695	1.5047	1.5638	0.039303
35	-1.2115	-1.1845	-1.116	0.040198	0.2424	0.26524	0.2898	0.016791	1.4058	1.4498	1.4751	0.032788
50	-1.1578	-1.1334	-1.0898	0.026124	0.263	0.30056	0.3672	0.040086	1.394	1.4339	1.525	0.053439
55	-1.2165	-1.1281	-1.0573	0.062116	0.2037	0.28134	0.3273	0.047896	1.3703	1.4095	1.4501	0.031931
100	-1.1603	-1.1343	-1.1079	0.023736	0.2736	0.35046	0.419	0.066974	1.3852	1.4848	1.5581	0.073602
105	-1.2234	-0.45656	2.3505	1.5704	0.4796	1.9485	6.3058	2.4578	1.5382	2.4051	3.9553	0.94032

Device Test: 34.14 _Enable|LeakageHigh/EN2/7/7///90.9/634//0///@EN_LKG_CURR





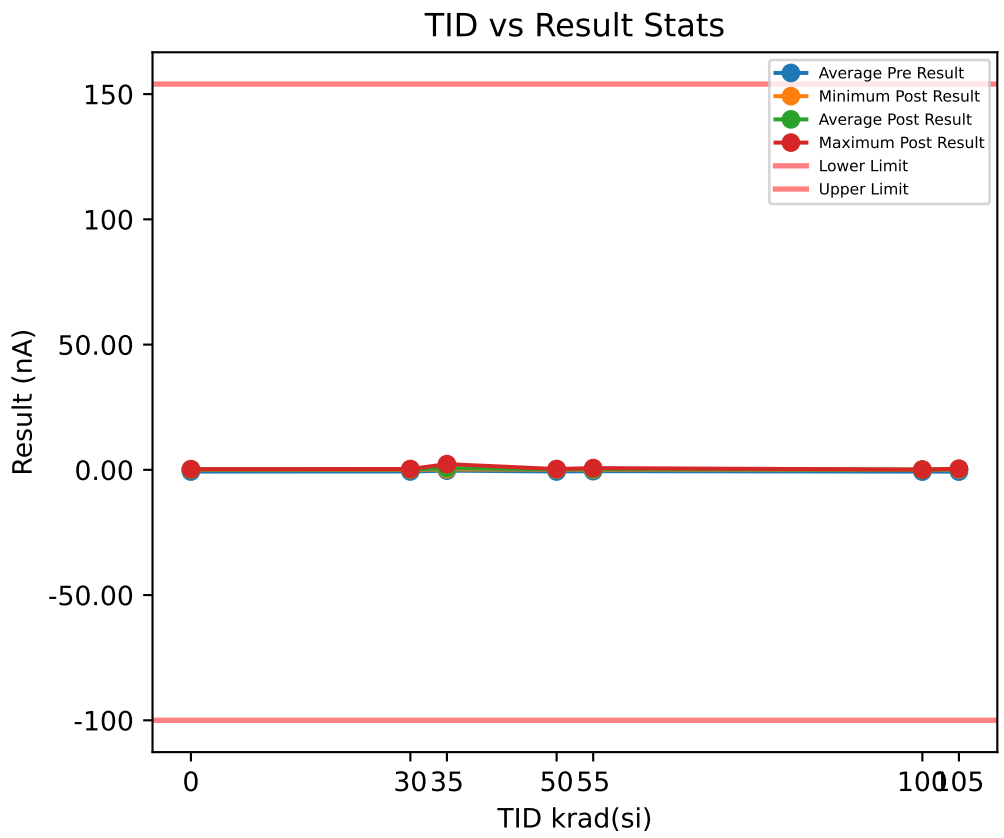
Test Results (Lower Limit = -100.0, Upper Limit = 154.0 (nA))

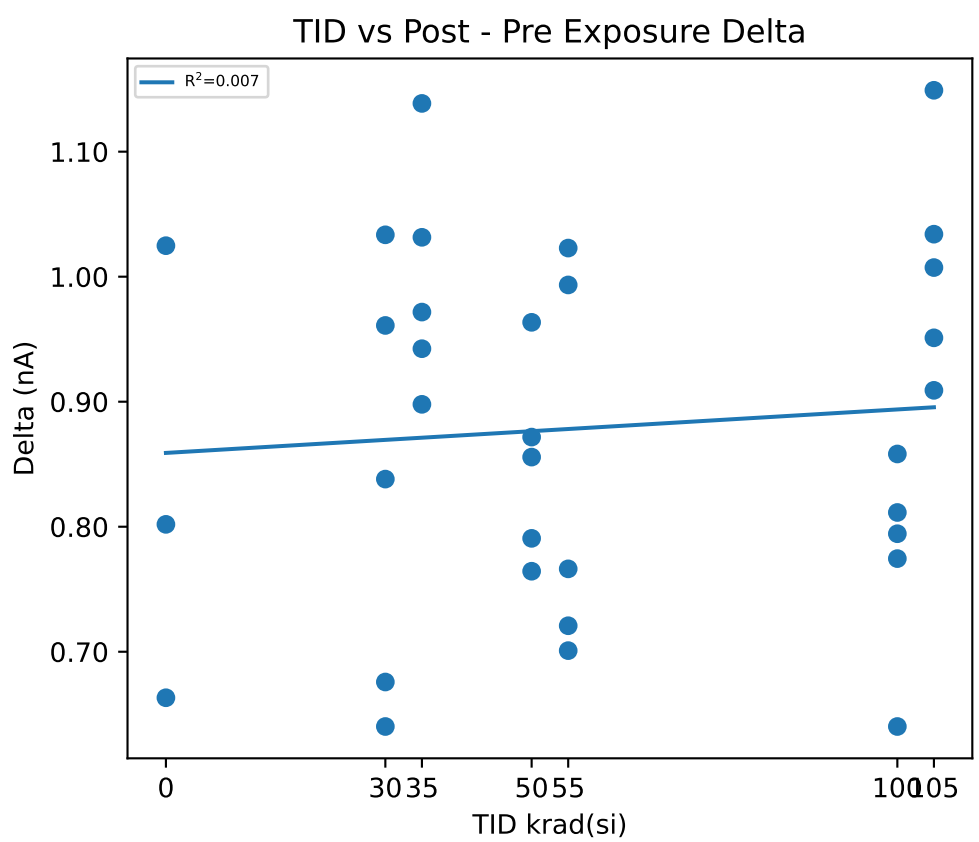
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.5652	0.4051	0.9703
2	0	CU2	0.0934	1.1051	1.0117
3	0	CU3	-0.5764	0.4813	1.0577
11	30	Unbiased-30krad	-0.5745	0.4619	1.0364
12	30	Unbiased-30krad	-0.6101	0.3864	0.9965
13	30	Unbiased-30krad	-0.4509	0.5206	0.9715
14	30	Unbiased-30krad	-0.5259	0.4238	0.9497
15	30	Unbiased-30krad	-0.6008	0.3501	0.9509
16	35	Biased-30krad	-0.4953	0.5518	1.0471
17	35	Biased-30krad	-0.6432	0.407	1.0502
18	35	Biased-30krad	-0.6314	0.4257	1.0571
19	35	Biased-30krad	-0.6488	0.4163	1.0651
20	35	Biased-30krad	-0.6207	0.3989	1.0196
30	50	Unbiased-50krad	-0.6014	0.3408	0.9422
31	50	Unbiased-50krad	-0.5059	0.5319	1.0378
32	50	Unbiased-50krad	-0.5646	0.422	0.9866
33	50	Unbiased-50krad	-0.5352	0.4382	0.9734
34	50	Unbiased-50krad	-0.5839	0.4482	1.0321
40	55	Biased-50krad	-0.5989	0.3945	0.9934
41	55	Biased-50krad	-0.5845	0.367	0.9515
42	55	Biased-50krad	-0.5184	0.4925	1.0109
43	55	Biased-50krad	-0.6363	0.4544	1.0907
44	55	Biased-50krad	-0.5621	0.4719	1.034
45	100	Unbiased-100krad	-0.529	0.5868	1.1158
46	100	Unbiased-100krad	-0.5964	0.4719	1.0683
47	100	Unbiased-100krad	-0.5989	0.3957	0.9946
48	100	Unbiased-100krad	-0.6039	0.4401	1.044
49	100	Unbiased-100krad	-0.6232	0.4032	1.0264
50	105	Biased-100krad	-0.6101	0.5531	1.1632
51	105	Biased-100krad	-0.6239	0.5306	1.1545
52	105	Biased-100krad	-0.6182	0.8553	1.4735
53	105	Biased-100krad	-0.5964	0.8522	1.4486
54	105	Biased-100krad	-0.1725	0.9596	1.1321

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.5764	-0.3494	0.0934	0.38352	0.4051	0.66383	1.1051	0.38404	0.9703	1.0132	1.0577	0.04372
30	-0.6101	-0.55244	-0.4509	0.065507	0.3501	0.42856	0.5206	0.066217	0.9497	0.981	1.0364	0.03635
35	-0.6488	-0.60788	-0.4953	0.063863	0.3989	0.43994	0.5518	0.063332	1.0196	1.0478	1.0651	0.017228
50	-0.6014	-0.5582	-0.5059	0.038184	0.3408	0.43622	0.5319	0.068208	0.9422	0.99442	1.0378	0.040409
55	-0.6363	-0.58004	-0.5184	0.043767	0.367	0.43606	0.4925	0.053157	0.9515	1.0161	1.0907	0.051481
100	-0.6232	-0.59028	-0.529	0.035834	0.3957	0.45954	0.5868	0.07742	0.9946	1.0498	1.1158	0.045625
105	-0.6239	-0.52422	-0.1725	0.19689	0.5306	0.75016	0.9596	0.19517	1.1321	1.2744	1.4735	0.17101

Device Test: 34.15 _Enable|LeakageHigh/EN3/7/7///90.9/634//0///@EN_LKG_CURR





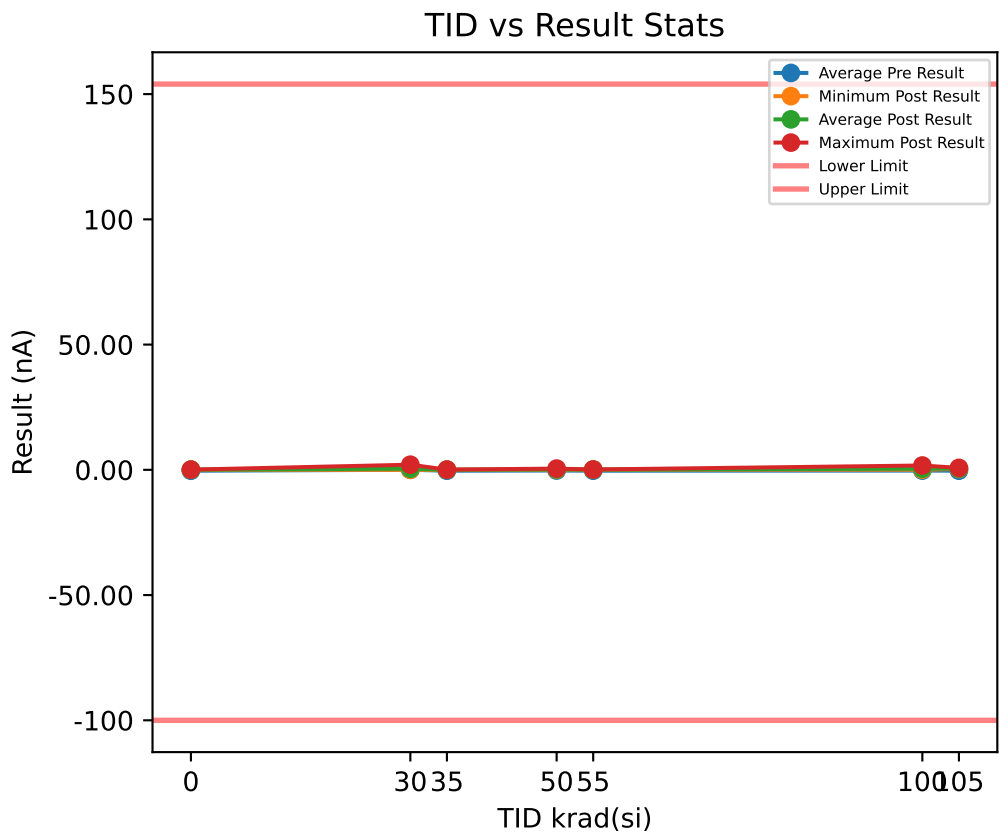
Test Results (Lower Limit = -100.0, Upper Limit = 154.0 (nA))

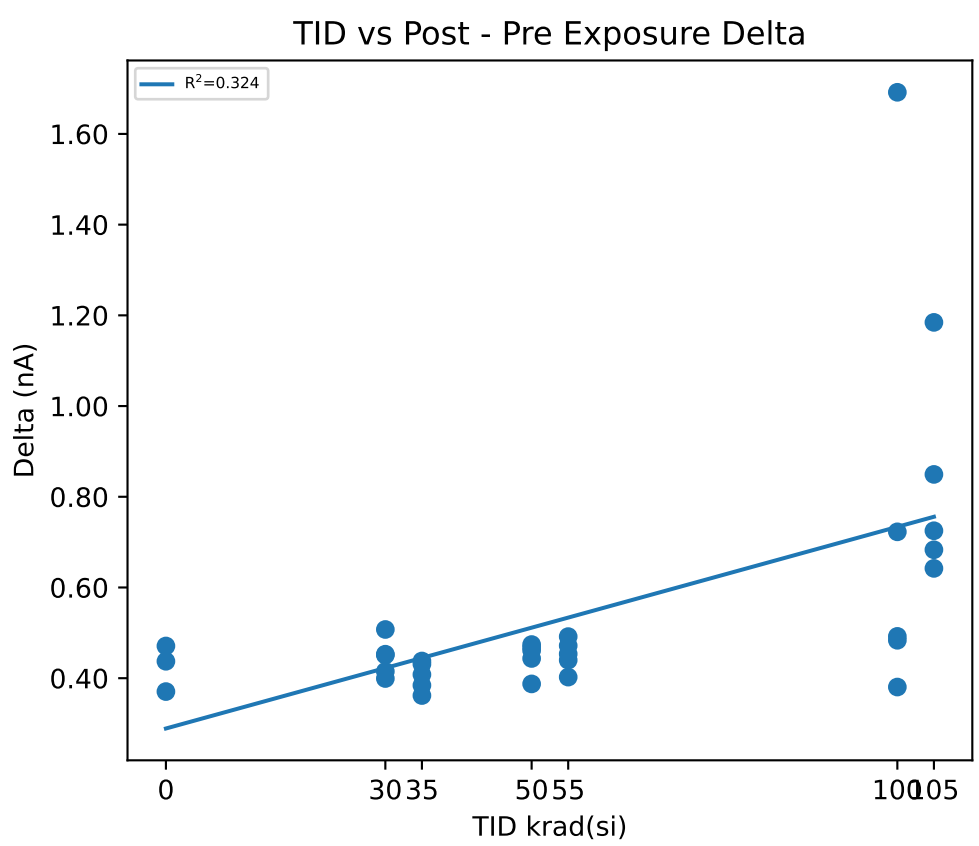
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.562	0.1012	0.6632
2	0	CU2	-0.7394	0.0625	0.8019
3	0	CU3	-0.7682	0.2566	1.0248
11	30	Unbiased-30krad	-0.6701	0.2909	0.961
12	30	Unbiased-30krad	-0.667	0.1711	0.8381
13	30	Unbiased-30krad	-0.6501	0.0257	0.6758
14	30	Unbiased-30krad	-0.6226	0.0176	0.6402
15	30	Unbiased-30krad	-0.7095	0.324	1.0335
16	35	Biased-30krad	-0.7682	0.1742	0.9424
17	35	Biased-30krad	-0.6988	0.3327	1.0315
18	35	Biased-30krad	-0.7201	0.2516	0.9717
19	35	Biased-30krad	1.1387	2.2773	1.1386
20	35	Biased-30krad	-0.5633	0.3346	0.8979
30	50	Unbiased-50krad	-0.7119	0.0788	0.7907
31	50	Unbiased-50krad	-0.622	0.1424	0.7644
32	50	Unbiased-50krad	-0.7457	0.11	0.8557
33	50	Unbiased-50krad	-0.6076	0.2641	0.8717
34	50	Unbiased-50krad	-0.6457	0.3178	0.9635
40	55	Biased-50krad	-0.647	0.0738	0.7208
41	55	Biased-50krad	-0.0087	0.6922	0.7009
42	55	Biased-50krad	-0.6863	0.08	0.7663
43	55	Biased-50krad	-0.5683	0.4251	0.9934
44	55	Biased-50krad	-0.7532	0.2697	1.0229
45	100	Unbiased-100krad	-0.5402	0.1	0.6402
46	100	Unbiased-100krad	-0.7338	0.0407	0.7745
47	100	Unbiased-100krad	-0.7244	0.07	0.7944
48	100	Unbiased-100krad	-0.8119	0.0463	0.8582
49	100	Unbiased-100krad	-0.7819	0.0295	0.8114
50	105	Biased-100krad	-0.7276	0.2797	1.0073
51	105	Biased-100krad	-0.8494	0.2997	1.1491
52	105	Biased-100krad	-0.5833	0.4507	1.034
53	105	Biased-100krad	-0.5951	0.314	0.9091
54	105	Biased-100krad	-0.8006	0.1505	0.9511

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.7682	-0.68987	-0.562	0.11167	0.0625	0.1401	0.2566	0.10273	0.6632	0.82997	1.0248	0.18243
30	-0.7095	-0.66386	-0.6226	0.031716	0.0176	0.16586	0.324	0.14344	0.6402	0.82972	1.0335	0.17208
35	-0.7682	-0.32234	1.1387	0.82028	0.1742	0.67408	2.2773	0.89868	0.8979	0.99642	1.1386	0.093114
50	-0.7457	-0.66658	-0.6076	0.059615	0.0788	0.18262	0.3178	0.10318	0.7644	0.8492	0.9635	0.077824
55	-0.7532	-0.5327	-0.0087	0.30047	0.0738	0.30816	0.6922	0.25963	0.7009	0.84086	1.0229	0.15489
100	-0.8119	-0.71844	-0.5402	0.10583	0.0295	0.0573	0.1	0.02808	0.6402	0.77574	0.8582	0.081841
105	-0.8494	-0.7112	-0.5833	0.11958	0.1505	0.29892	0.4507	0.10684	0.9091	1.0101	1.1491	0.091627

Device Test: 34.16 _Enable|LeakageHigh/EN4/7/7///90.9/634//0///@EN_LKG_CURR





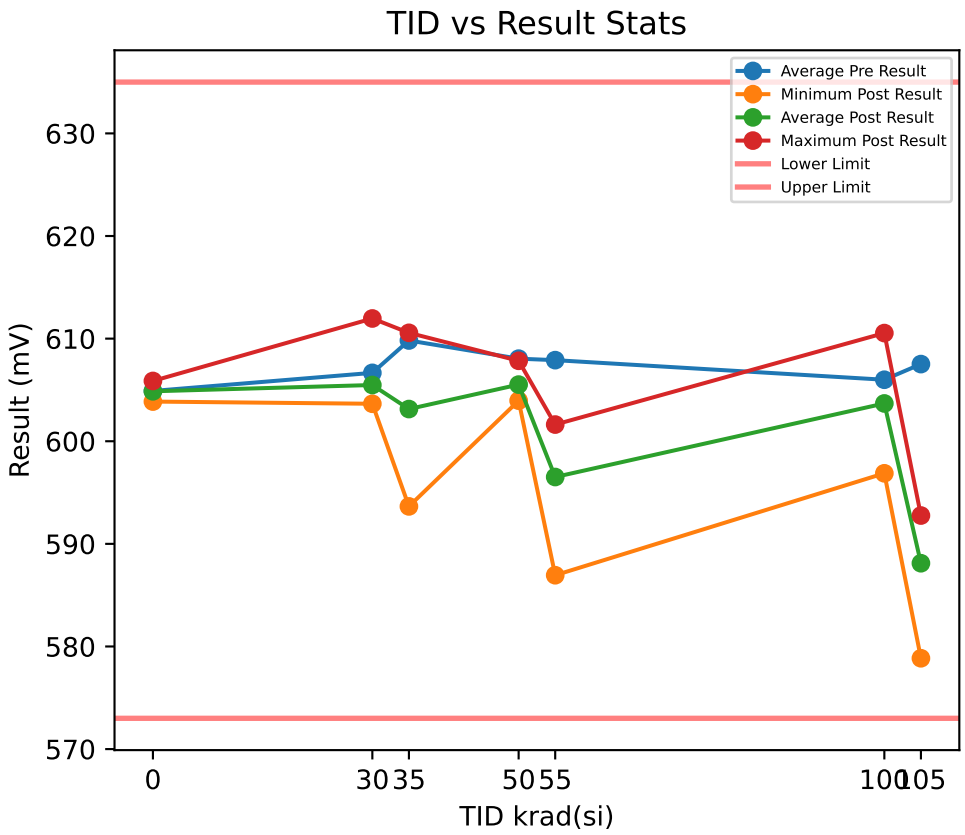
Test Results (Lower Limit = -100.0, Upper Limit = 154.0 (nA))

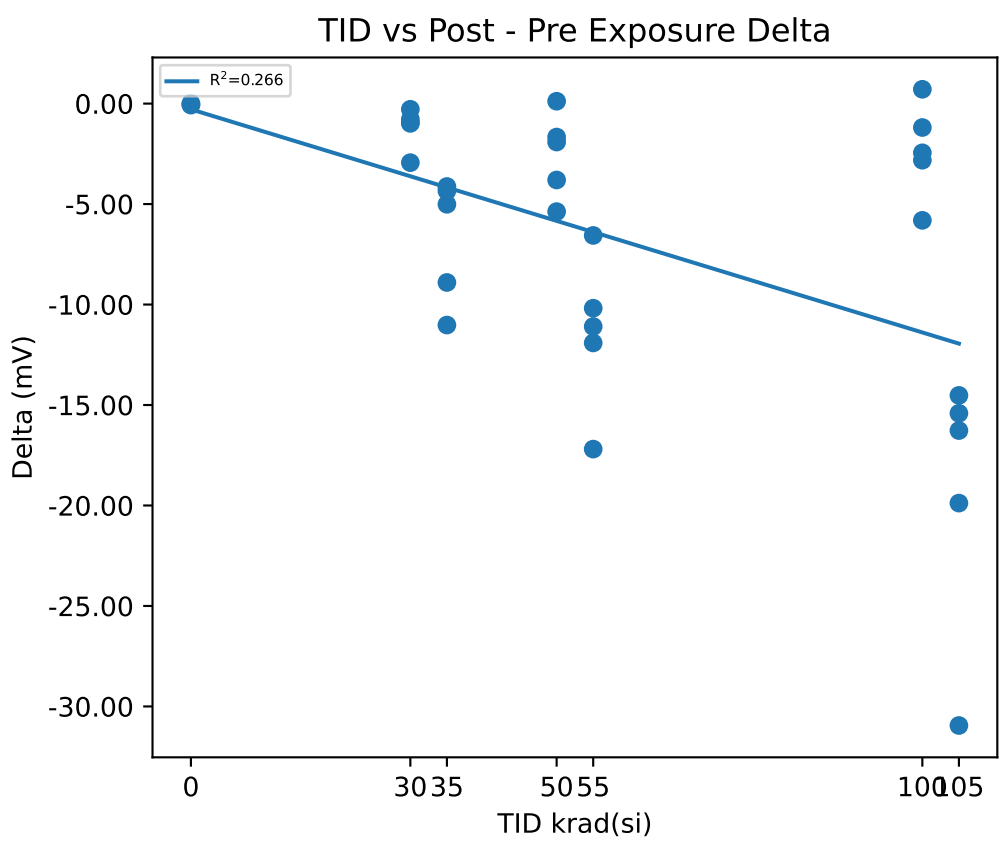
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.2859	0.0846	0.3705
2	0	CU2	-0.3796	0.0577	0.4373
3	0	CU3	-0.427	0.044	0.471
11	30	Unbiased-30krad	-0.3659	0.0334	0.3993
12	30	Unbiased-30krad	-0.2703	0.1807	0.451
13	30	Unbiased-30krad	1.5384	2.0458	0.5074
14	30	Unbiased-30krad	-0.4158	0.0371	0.4529
15	30	Unbiased-30krad	-0.4183	-0.0034	0.4149
16	35	Biased-30krad	-0.3852	0.0228	0.408
17	35	Biased-30krad	-0.4064	0.0315	0.4379
18	35	Biased-30krad	-0.344	0.0871	0.4311
19	35	Biased-30krad	-0.3222	0.0621	0.3843
20	35	Biased-30krad	-0.3228	0.039	0.3618
30	50	Unbiased-50krad	-0.3446	0.0428	0.3874
31	50	Unbiased-50krad	-0.3659	0.1083	0.4742
32	50	Unbiased-50krad	0.0219	0.4897	0.4678
33	50	Unbiased-50krad	-0.4052	0.0559	0.4611
34	50	Unbiased-50krad	-0.3165	0.127	0.4435
40	55	Biased-50krad	-0.344	0.0958	0.4398
41	55	Biased-50krad	-0.3303	0.0721	0.4024
42	55	Biased-50krad	-0.3609	0.1308	0.4917
43	55	Biased-50krad	-0.3833	0.0702	0.4535
44	55	Biased-50krad	-0.3384	0.1333	0.4717
45	100	Unbiased-100krad	-0.3259	0.0546	0.3805
46	100	Unbiased-100krad	0.0344	1.7262	1.6918
47	100	Unbiased-100krad	-0.4789	0.2438	0.7227
48	100	Unbiased-100krad	-0.3659	0.1177	0.4836
49	100	Unbiased-100krad	-0.4039	0.0883	0.4922
50	105	Biased-100krad	-0.261	0.3811	0.6421
51	105	Biased-100krad	-0.3459	0.3792	0.7251
52	105	Biased-100krad	-0.4033	0.7812	1.1845
53	105	Biased-100krad	-0.3908	0.4585	0.8493
54	105	Biased-100krad	-0.3371	0.3461	0.6832

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.427	-0.36417	-0.2859	0.071805	0.044	0.0621	0.0846	0.020655	0.3705	0.42627	0.471	0.05115
30	-0.4183	0.01362	1.5384	0.85448	-0.0034	0.45872	2.0458	0.88999	0.3993	0.4451	0.5074	0.041793
35	-0.4064	-0.35612	-0.3222	0.038018	0.0228	0.0485	0.0871	0.026051	0.3618	0.40462	0.4379	0.031885
50	-0.4052	-0.28206	0.0219	0.17298	0.0428	0.16474	0.4897	0.18502	0.3874	0.4468	0.4742	0.035127
55	-0.3833	-0.35138	-0.3303	0.021076	0.0702	0.10044	0.1333	0.03058	0.4024	0.45182	0.4917	0.03382
100	-0.4789	-0.30804	0.0344	0.19957	0.0546	0.44612	1.7262	0.71915	0.3805	0.75416	1.6918	0.53889
105	-0.4033	-0.34762	-0.261	0.056083	0.3461	0.46922	0.7812	0.17922	0.6421	0.81684	1.1845	0.21968

Device Test: 34.2 _Enable|RisingThreshold/EN2/7/7///90.9/634//0///@EN_VTH_RISING





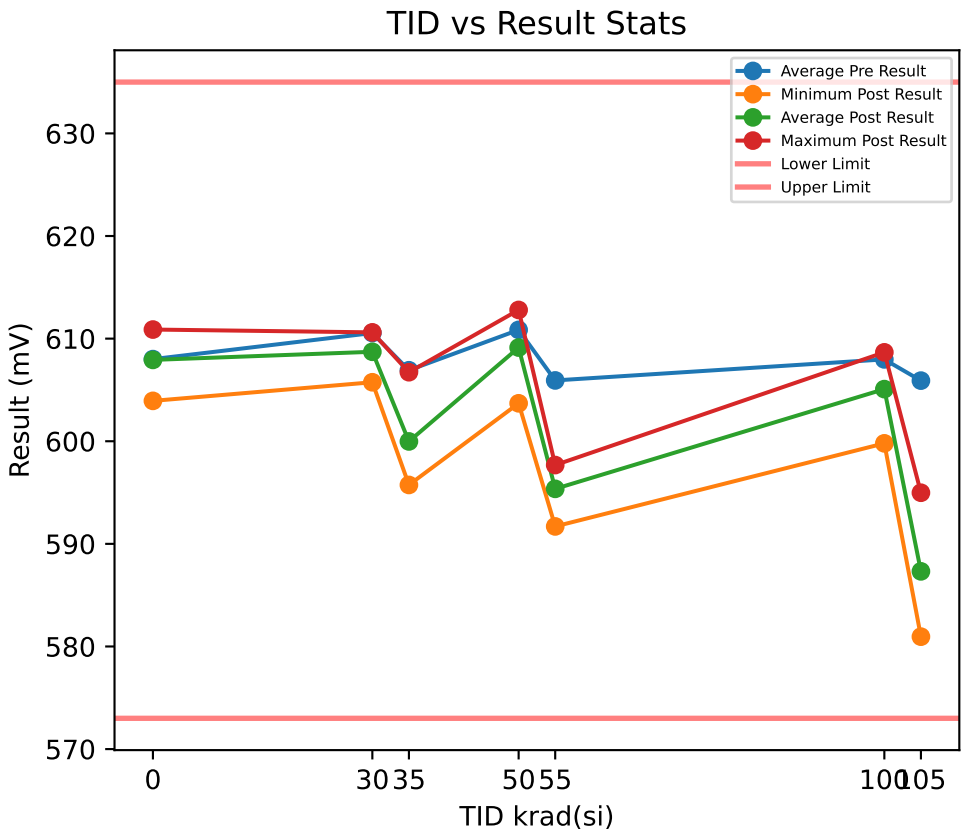
Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

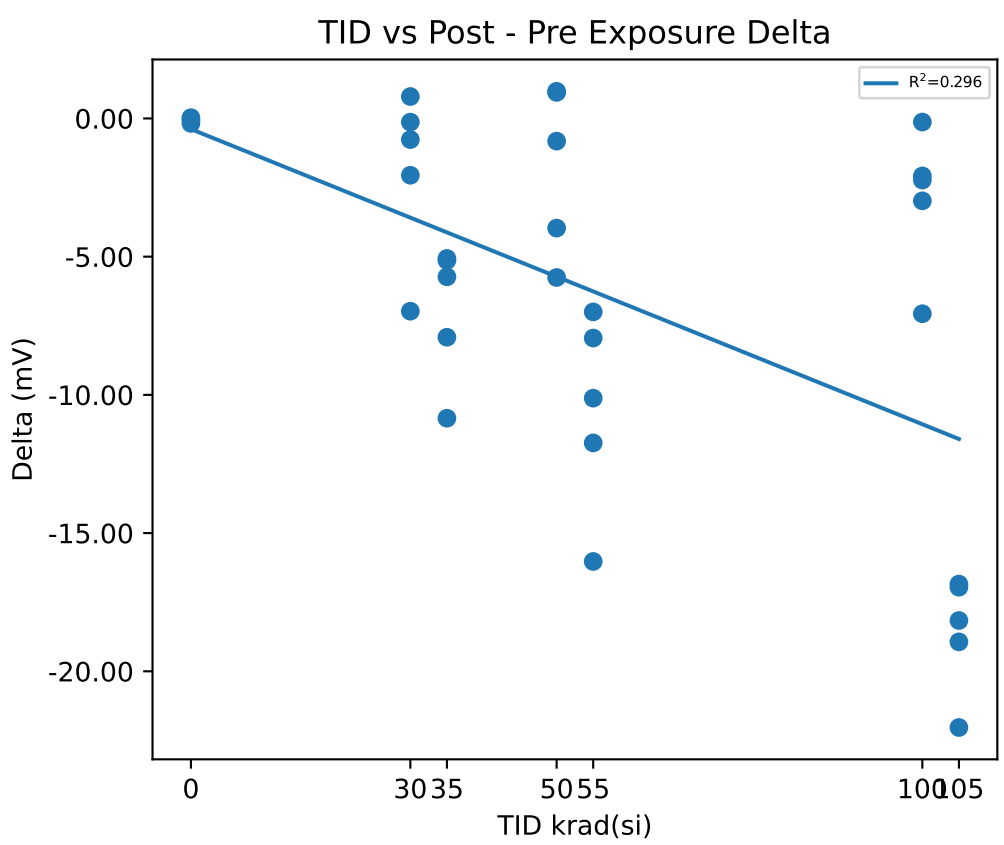
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	604.94	604.86	-0.0759
2	0	CU2	603.86	603.87	0.0108
3	0	CU3	605.91	605.87	-0.0396
11	30	Unbiased-30krad	603.93	603.65	-0.282
12	30	Unbiased-30krad	612.74	611.96	-0.7761
13	30	Unbiased-30krad	604.86	603.92	-0.9401
14	30	Unbiased-30krad	606.87	603.94	-2.9387
15	30	Unbiased-30krad	604.91	603.93	-0.985
16	35	Biased-30krad	606.98	602.85	-4.1253
17	35	Biased-30krad	602.55	593.65	-8.9015
18	35	Biased-30krad	615.86	604.84	-11.02
19	35	Biased-30krad	614.91	610.56	-4.3444
20	35	Biased-30krad	608.79	603.78	-5.0108
30	50	Unbiased-50krad	605.79	605.91	0.1181
31	50	Unbiased-50krad	609.75	607.84	-1.9132
32	50	Unbiased-50krad	606.59	604.93	-1.6641
33	50	Unbiased-50krad	607.76	603.96	-3.8014
34	50	Unbiased-50krad	610.34	604.97	-5.3755
40	55	Biased-50krad	609.76	597.85	-11.911
41	55	Biased-50krad	604.14	586.94	-17.194
42	55	Biased-50krad	608.85	598.67	-10.183
43	55	Biased-50krad	608.58	597.49	-11.093
44	55	Biased-50krad	608.19	601.63	-6.5606
45	100	Unbiased-100krad	609.83	610.54	0.712
46	100	Unbiased-100krad	606.95	605.76	-1.1901
47	100	Unbiased-100krad	606.76	604.31	-2.4494
48	100	Unbiased-100krad	602.69	596.88	-5.8092
49	100	Unbiased-100krad	603.75	600.94	-2.8174
50	105	Biased-100krad	608.93	592.66	-16.27
51	105	Biased-100krad	609.8	578.85	-30.949
52	105	Biased-100krad	608.17	592.76	-15.412
53	105	Biased-100krad	606.84	592.32	-14.521
54	105	Biased-100krad	603.86	583.98	-19.881

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	603.86	604.9	605.91	1.03	603.87	604.87	605.87	1.0044	-0.0759	-0.0349	0.0108	0.043541
30	603.93	606.66	612.74	3.5614	603.65	605.48	611.96	3.6266	-2.9387	-1.1844	-0.282	1.0196
35	602.55	609.82	615.86	5.5768	593.65	603.14	610.56	6.0943	-11.02	-6.6804	-4.1253	3.104
50	605.79	608.05	610.34	1.9671	603.96	605.52	607.84	1.4692	-5.3755	-2.5272	0.1181	2.1128
55	604.14	607.9	609.76	2.1832	586.94	596.51	601.63	5.5923	-17.194	-11.388	-6.5606	3.8349
100	602.69	605.99	609.83	2.8358	596.88	603.68	610.54	5.1383	-5.8092	-2.3108	0.712	2.3931
105	603.86	607.52	609.8	2.3179	578.85	588.11	592.76	6.3797	-30.949	-19.407	-14.521	6.7659

Device Test: 34.3 _Enable|RisingThreshold/EN3/7/7///90.9/634//0///@EN_VTH_RISING





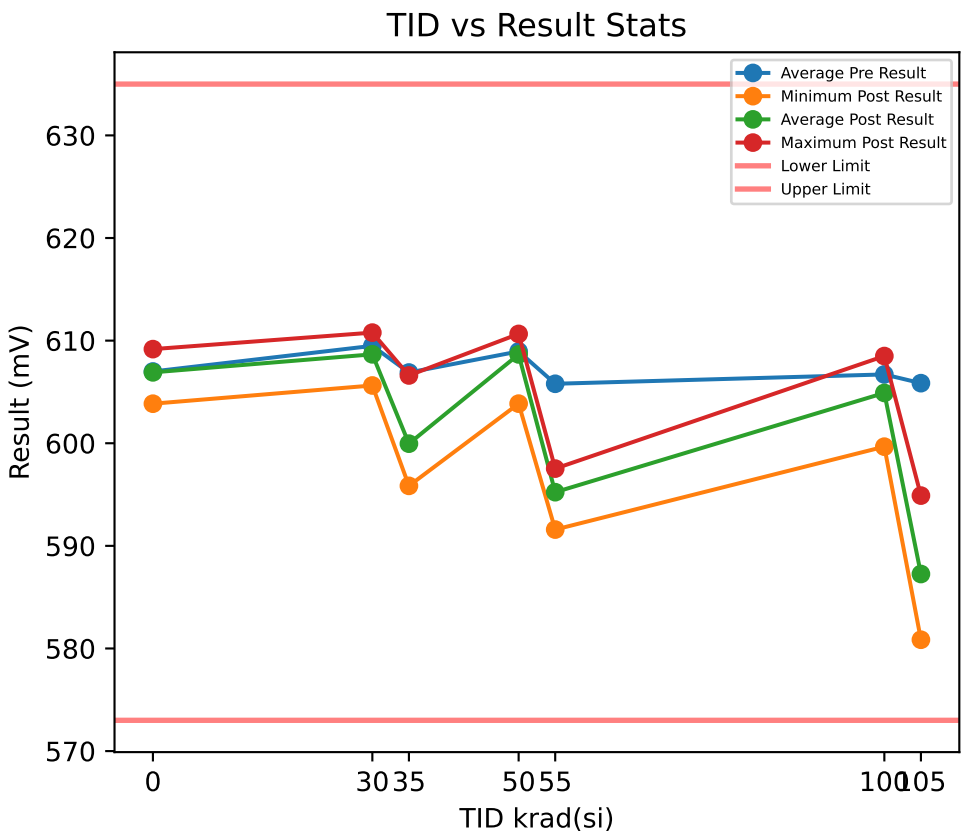
Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

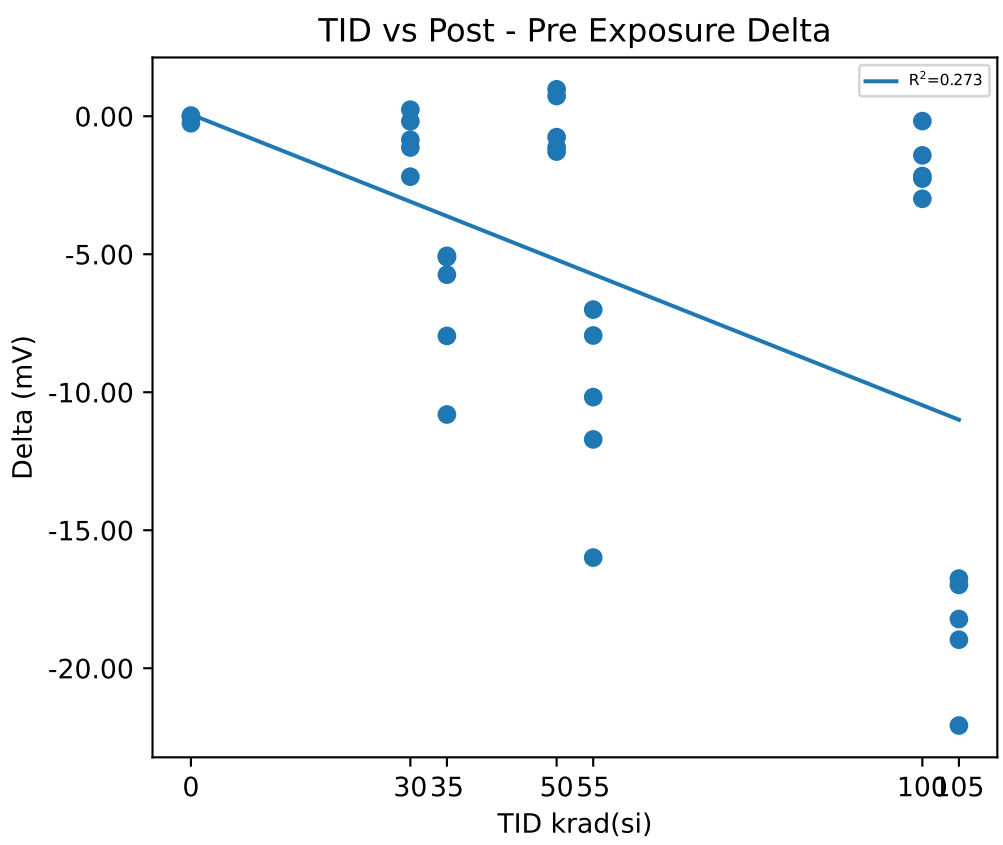
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	610.96	610.88	-0.0751
2	0	CU2	609.14	608.96	-0.1791
3	0	CU3	603.91	603.93	0.0272
11	30	Unbiased-30krad	609.65	608.89	-0.7641
12	30	Unbiased-30krad	605.88	605.75	-0.1325
13	30	Unbiased-30krad	609.82	610.61	0.7926
14	30	Unbiased-30krad	612.64	610.58	-2.0553
15	30	Unbiased-30krad	614.73	607.75	-6.9731
16	35	Biased-30krad	611.79	606.73	-5.0647
17	35	Biased-30krad	608.64	597.8	-10.844
18	35	Biased-30krad	605.74	600.61	-5.1349
19	35	Biased-30krad	603.66	595.74	-7.9149
20	35	Biased-30krad	604.76	599.03	-5.7286
30	50	Unbiased-50krad	602.71	603.7	0.9824
31	50	Unbiased-50krad	611.85	612.79	0.943
32	50	Unbiased-50krad	610.48	609.66	-0.8206
33	50	Unbiased-50krad	613.74	609.77	-3.967
34	50	Unbiased-50krad	615.49	609.73	-5.7529
40	55	Biased-50krad	604.79	593.06	-11.738
41	55	Biased-50krad	607.73	591.7	-16.026
42	55	Biased-50krad	606.87	596.75	-10.119
43	55	Biased-50krad	605.56	597.62	-7.9441
44	55	Biased-50krad	604.68	597.68	-6.9985
45	100	Unbiased-100krad	606.74	603.76	-2.9807
46	100	Unbiased-100krad	610.89	608.66	-2.2289
47	100	Unbiased-100krad	609.59	607.51	-2.0794
48	100	Unbiased-100krad	599.93	599.8	-0.1303
49	100	Unbiased-100krad	612.73	605.66	-7.0645
50	105	Biased-100krad	611.83	594.98	-16.844
51	105	Biased-100krad	602.99	580.96	-22.033
52	105	Biased-100krad	604.83	585.89	-18.934
53	105	Biased-100krad	603.93	585.77	-18.162
54	105	Biased-100krad	605.97	589.01	-16.958

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	603.91	608	610.96	3.6615	603.93	607.93	610.88	3.5888	-0.1791	-0.075667	0.0272	0.10315
30	605.88	610.54	614.73	3.353	605.75	608.72	610.61	2.0523	-6.9731	-1.8265	0.7926	3.0577
35	603.66	606.92	611.79	3.2941	595.74	599.98	606.73	4.1694	-10.844	-6.9374	-5.0647	2.4716
50	602.71	610.85	615.49	4.928	603.7	609.13	612.79	3.3166	-5.7529	-1.723	0.9824	3.0215
55	604.68	605.93	607.73	1.3329	591.7	595.36	597.68	2.789	-16.026	-10.565	-6.9985	3.5704
100	599.93	607.98	612.73	5.0003	599.8	605.08	608.66	3.4915	-7.0645	-2.8968	-0.1303	2.5566
105	602.99	605.91	611.83	3.4867	580.96	587.32	594.98	5.1601	-22.033	-18.586	-16.844	2.1136

Device Test: 34.4 _Enable|RisingThreshold/EN4/7/7///90.9/634//0///@EN_VTH_RISING





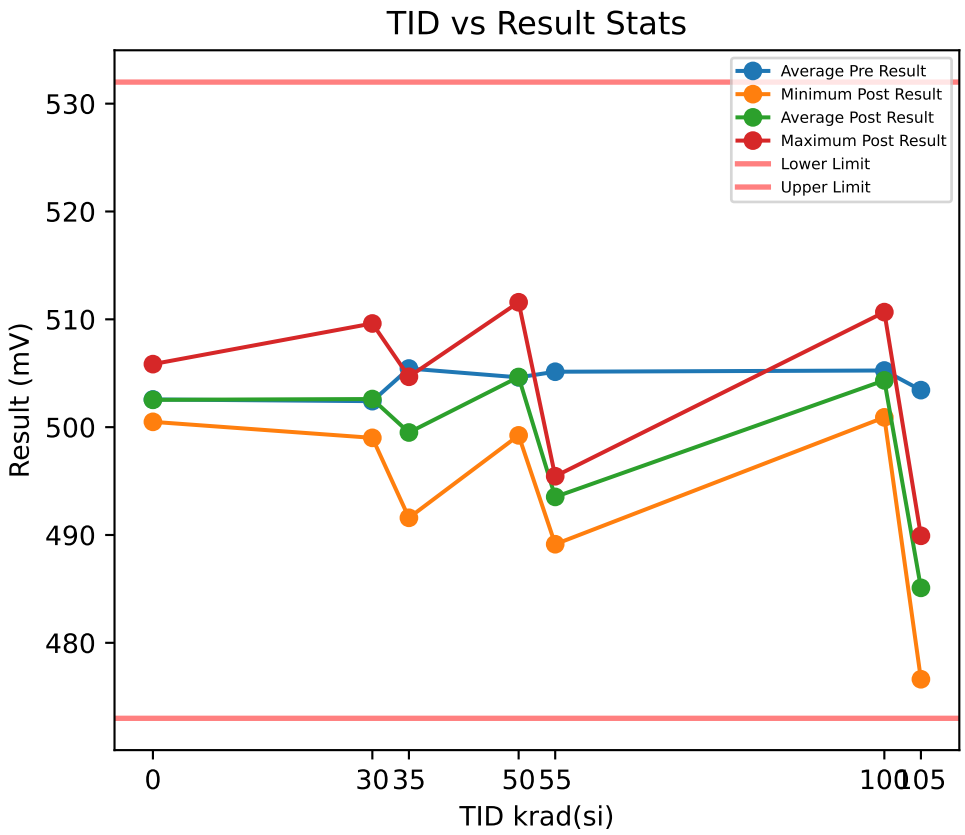
Test Results (Lower Limit = 573.0, Upper Limit = 635.0 (mV))

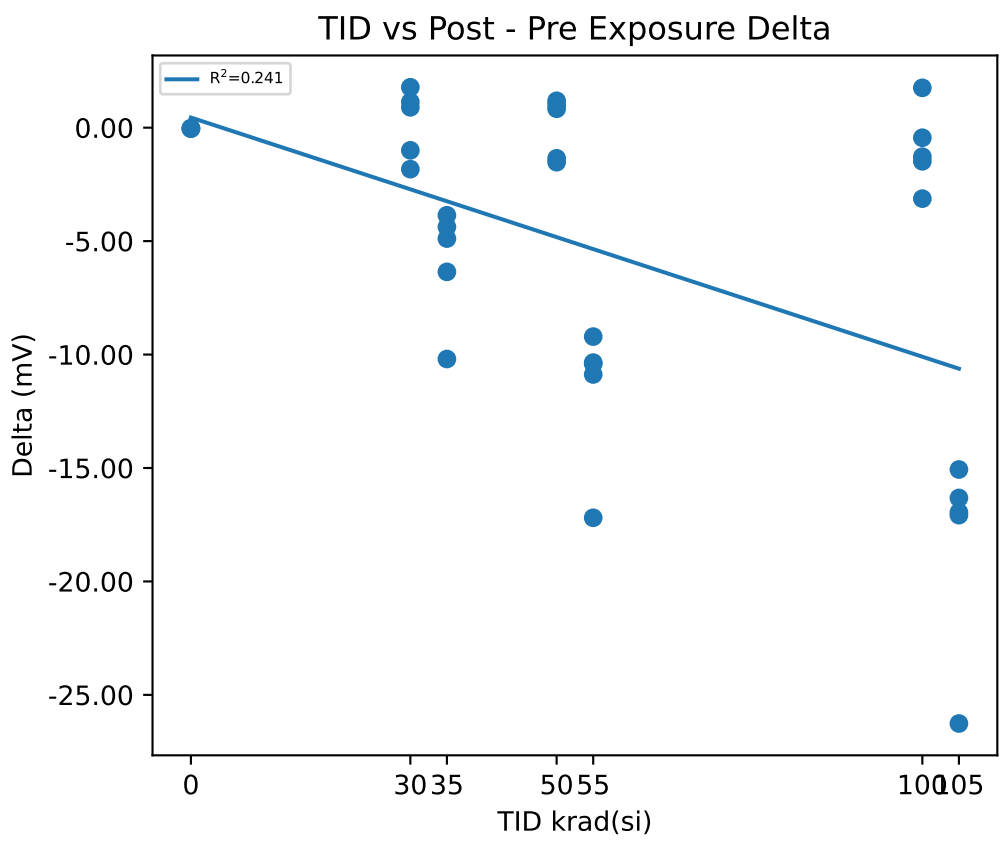
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	607.73	607.7	-0.028
2	0	CU2	609.43	609.17	-0.2537
3	0	CU3	603.83	603.85	0.0251
11	30	Unbiased-30krad	609.8	608.94	-0.8529
12	30	Unbiased-30krad	605.81	605.63	-0.1846
13	30	Unbiased-30krad	610.54	610.78	0.2382
14	30	Unbiased-30krad	612.53	610.34	-2.1905
15	30	Unbiased-30krad	608.76	607.62	-1.1339
16	35	Biased-30krad	611.66	606.61	-5.0573
17	35	Biased-30krad	608.5	597.69	-10.806
18	35	Biased-30krad	605.85	600.75	-5.1061
19	35	Biased-30krad	603.81	595.85	-7.959
20	35	Biased-30krad	604.65	598.91	-5.7411
30	50	Unbiased-50krad	602.88	603.86	0.9767
31	50	Unbiased-50krad	611.78	610.65	-1.1243
32	50	Unbiased-50krad	610.29	609.53	-0.7576
33	50	Unbiased-50krad	608.9	609.63	0.733
34	50	Unbiased-50krad	610.89	609.61	-1.2798
40	55	Biased-50krad	604.66	592.95	-11.709
41	55	Biased-50krad	607.58	591.59	-15.99
42	55	Biased-50krad	606.78	596.6	-10.177
43	55	Biased-50krad	605.43	597.49	-7.9437
44	55	Biased-50krad	604.53	597.53	-7.0056
45	100	Unbiased-100krad	606.63	603.64	-2.9916
46	100	Unbiased-100krad	610.76	608.5	-2.2594
47	100	Unbiased-100krad	609.42	607.26	-2.1655
48	100	Unbiased-100krad	599.84	599.67	-0.1757
49	100	Unbiased-100krad	606.87	605.46	-1.4177
50	105	Biased-100krad	611.65	594.9	-16.751
51	105	Biased-100krad	602.93	580.85	-22.075
52	105	Biased-100krad	604.92	585.95	-18.966
53	105	Biased-100krad	603.86	585.64	-18.218
54	105	Biased-100krad	605.92	588.94	-16.982

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	603.83	606.99	609.43	2.8698	603.85	606.91	609.17	2.746	-0.2537	-0.085533	0.0251	0.14804
30	605.81	609.49	612.53	2.4763	605.63	608.66	610.78	2.1024	-2.1905	-0.82474	0.2382	0.93559
35	603.81	606.89	611.66	3.2005	595.85	599.96	606.61	4.1217	-10.806	-6.934	-5.0573	2.4664
50	602.88	608.95	611.78	3.5488	603.86	608.66	610.65	2.7217	-1.2798	-0.2904	0.9767	1.066
55	604.53	605.8	607.58	1.3375	591.59	595.23	597.53	2.7721	-15.99	-10.565	-7.0056	3.5509
100	599.84	606.71	610.76	4.2109	599.67	604.9	608.5	3.456	-2.9916	-1.802	-0.1757	1.0664
105	602.93	605.86	611.65	3.4276	580.85	587.26	594.9	5.1607	-22.075	-18.598	-16.751	2.1444

Device Test: 34.5 _Enable|FallingThreshold/EN1/7/7///90.9/634//0///@EN_VTH_FALLING





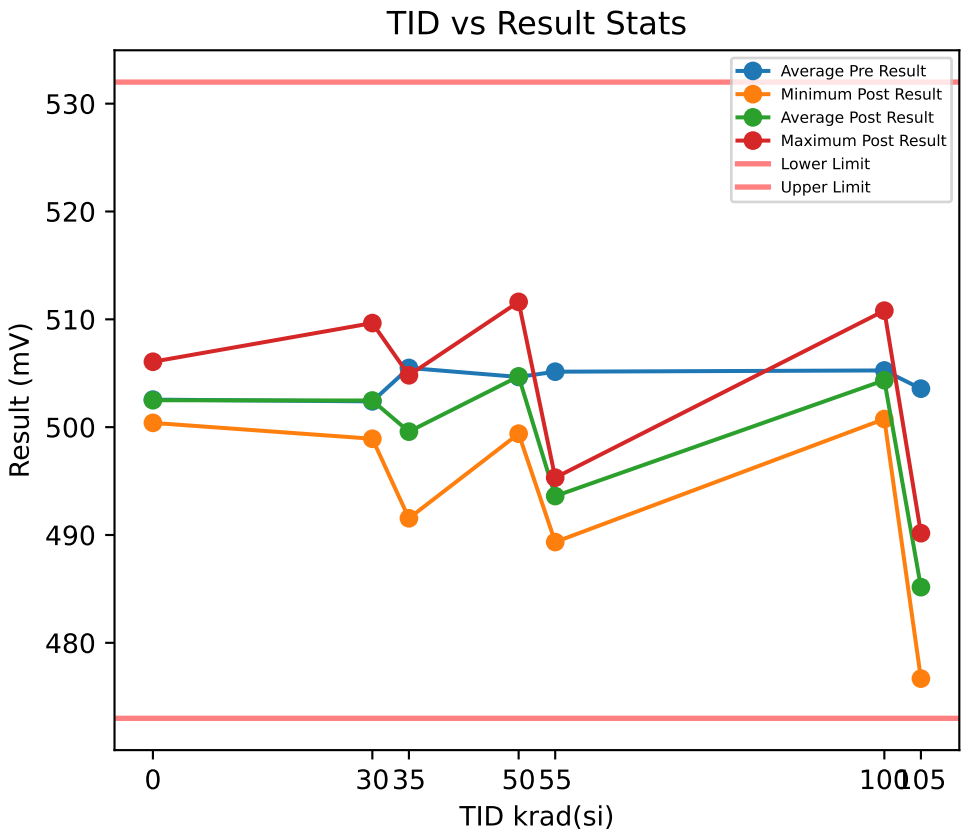
Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

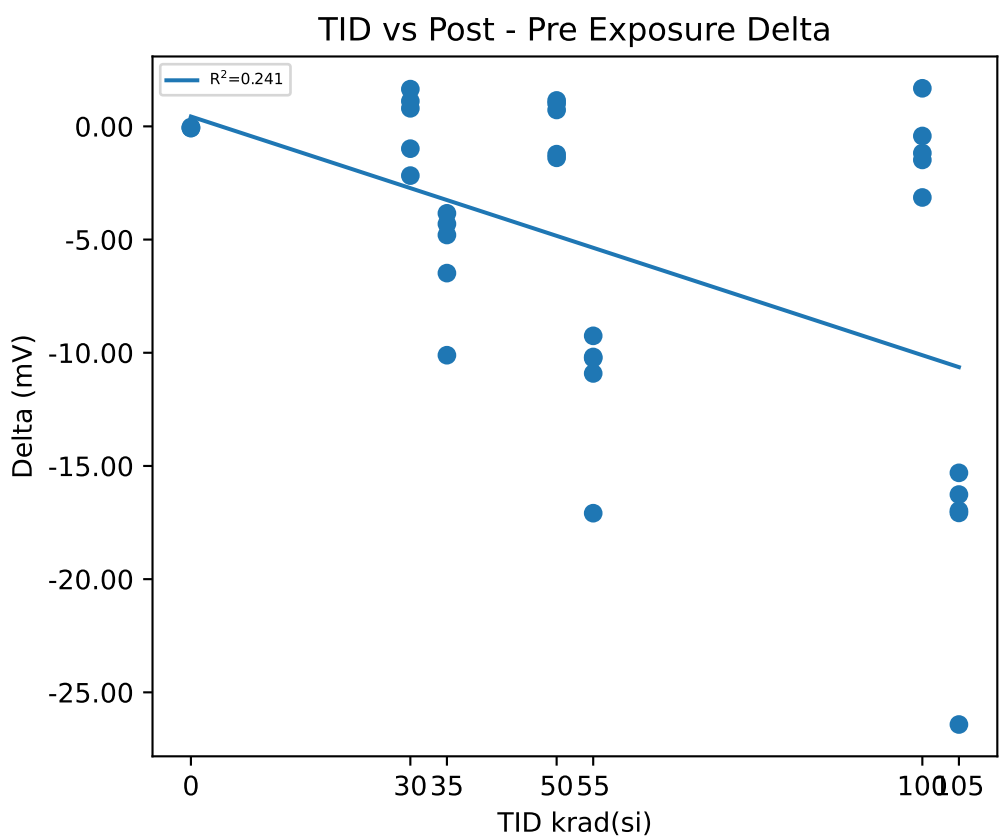
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	501.31	501.27	-0.0417
2	0	CU2	505.88	505.84	-0.039
3	0	CU3	500.51	500.49	-0.0201
11	30	Unbiased-30krad	501.81	502.95	1.1367
12	30	Unbiased-30krad	507.83	509.61	1.7802
13	30	Unbiased-30krad	500.32	501.22	0.8972
14	30	Unbiased-30krad	502.08	500.25	-1.8283
15	30	Unbiased-30krad	500.01	499.01	-0.9983
16	35	Biased-30krad	502.9	499.04	-3.8595
17	35	Biased-30krad	501.79	491.59	-10.196
18	35	Biased-30krad	510.02	503.67	-6.3549
19	35	Biased-30krad	509.56	504.67	-4.888
20	35	Biased-30krad	502.92	498.54	-4.3741
30	50	Unbiased-50krad	510.75	511.58	0.8341
31	50	Unbiased-50krad	506.26	507.45	1.185
32	50	Unbiased-50krad	502.08	500.56	-1.5222
33	50	Unbiased-50krad	500.59	499.24	-1.3505
34	50	Unbiased-50krad	503.41	504.42	1.0154
40	55	Biased-50krad	505.43	495.08	-10.354
41	55	Biased-50krad	506.34	489.14	-17.195
42	55	Biased-50krad	504.66	495.45	-9.2085
43	55	Biased-50krad	503.97	493.09	-10.877
44	55	Biased-50krad	505.31	494.9	-10.406
45	100	Unbiased-100krad	505.53	504.26	-1.2788
46	100	Unbiased-100krad	508.91	510.67	1.7557
47	100	Unbiased-100krad	504.58	501.45	-3.128
48	100	Unbiased-100krad	502.39	500.91	-1.4825
49	100	Unbiased-100krad	504.86	504.41	-0.4436
50	105	Biased-100krad	503.34	488.28	-15.066
51	105	Biased-100krad	502.88	476.62	-26.262
52	105	Biased-100krad	506.87	489.92	-16.95
53	105	Biased-100krad	503.59	487.27	-16.321
54	105	Biased-100krad	500.47	483.39	-17.079

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.51	502.57	505.88	2.8989	500.49	502.53	505.84	2.8928	-0.0417	-0.0336	-0.0201	0.011769
30	500.01	502.41	507.83	3.1633	499.01	502.61	509.61	4.1726	-1.8283	0.1975	1.7802	1.5338
35	501.79	505.44	510.02	4.0037	491.59	499.5	504.67	5.1908	-10.196	-5.9344	-3.8595	2.5578
50	500.59	504.62	510.75	4.0126	499.24	504.65	511.58	5.0481	-1.5222	0.03236	1.185	1.3478
55	503.97	505.14	506.34	0.88834	489.14	493.53	495.45	2.617	-17.195	-11.608	-9.2085	3.1827
100	502.39	505.25	508.91	2.3601	500.91	504.34	510.67	3.8793	-3.128	-0.91544	1.7557	1.7823
105	500.47	503.43	506.87	2.2878	476.62	485.1	489.92	5.3123	-26.262	-18.336	-15.066	4.5019

Device Test: 34.6 _Enable|FallingThreshold/EN2/7/7///90.9/634//0///@EN_VTH_FALLING





Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

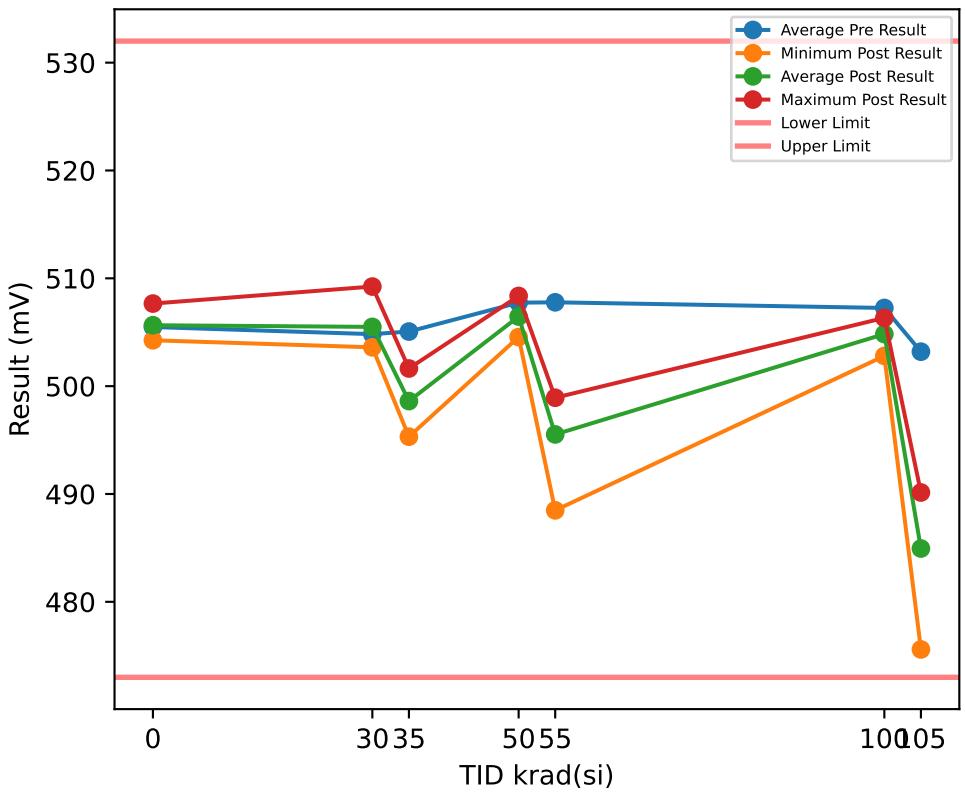
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	501.1	501.02	-0.0769
2	0	CU2	506.13	506.07	-0.0665
3	0	CU3	500.43	500.4	-0.0288
11	30	Unbiased-30krad	501.68	502.8	1.1154
12	30	Unbiased-30krad	508.01	509.65	1.6458
13	30	Unbiased-30krad	500.17	500.97	0.7974
14	30	Unbiased-30krad	502.19	500.01	-2.1743
15	30	Unbiased-30krad	499.91	498.92	-0.9846
16	35	Biased-30krad	503.13	499.29	-3.8404
17	35	Biased-30krad	501.66	491.55	-10.108
18	35	Biased-30krad	510.29	503.81	-6.4818
19	35	Biased-30krad	509.61	504.81	-4.7982
20	35	Biased-30krad	502.77	498.46	-4.3092
30	50	Unbiased-50krad	510.89	511.62	0.725
31	50	Unbiased-50krad	506.38	507.52	1.1458
32	50	Unbiased-50krad	501.9	500.51	-1.3887
33	50	Unbiased-50krad	500.62	499.39	-1.2274
34	50	Unbiased-50krad	503.49	504.49	1.0073
40	55	Biased-50krad	505.49	495.31	-10.186
41	55	Biased-50krad	506.43	489.35	-17.087
42	55	Biased-50krad	504.57	495.31	-9.2522
43	55	Biased-50krad	503.81	492.9	-10.913
44	55	Biased-50krad	505.41	495.17	-10.237
45	100	Unbiased-100krad	505.57	504.39	-1.1804
46	100	Unbiased-100krad	509.12	510.81	1.6823
47	100	Unbiased-100krad	504.66	501.52	-3.1405
48	100	Unbiased-100krad	502.24	500.75	-1.4816
49	100	Unbiased-100krad	504.71	504.28	-0.4243
50	105	Biased-100krad	503.38	488.07	-15.304
51	105	Biased-100krad	503.1	476.68	-26.421
52	105	Biased-100krad	507.14	490.17	-16.976
53	105	Biased-100krad	503.68	487.42	-16.262
54	105	Biased-100krad	500.54	483.46	-17.074

Test Statistics (mV)

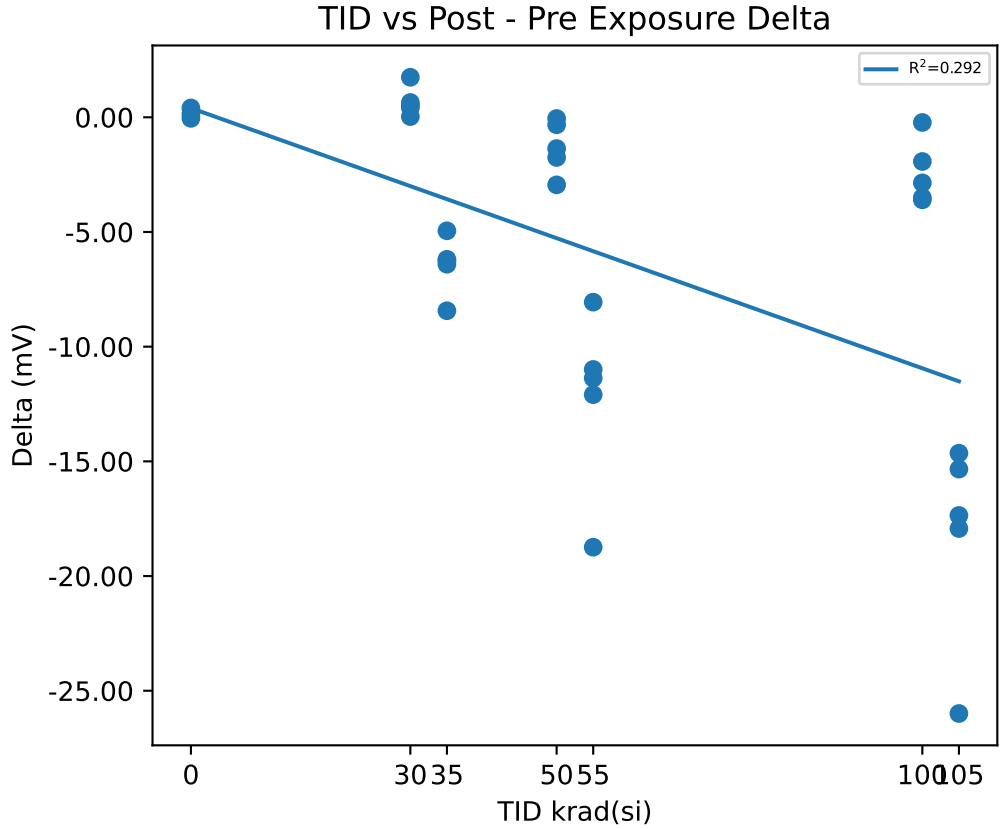
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	500.43	502.55	506.13	3.1181	500.4	502.5	506.07	3.1078	-0.0769	-0.0574	-0.0288	0.025308
30	499.91	502.39	508.01	3.2842	498.92	502.47	509.65	4.2584	-2.1743	0.07994	1.6458	1.6011
35	501.66	505.49	510.29	4.1125	491.55	499.58	504.81	5.2691	-10.108	-5.9076	-3.8404	2.5512
50	500.62	504.66	510.89	4.0963	499.39	504.71	511.62	5.0395	-1.3887	0.0524	1.1458	1.2524
55	503.81	505.14	506.43	0.99465	489.35	493.61	495.31	2.5949	-17.087	-11.535	-9.2522	3.1592
100	502.24	505.26	509.12	2.4916	500.75	504.35	510.81	3.9565	-3.1405	-0.9089	1.6823	1.7558
105	500.54	503.57	507.14	2.3575	476.68	485.16	490.17	5.3258	-26.421	-18.407	-15.304	4.5351

Device Test: 34.7 _Enable|FallingThreshold/EN3/7/7///90.9/634//0///@EN_VTH_FALLING

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

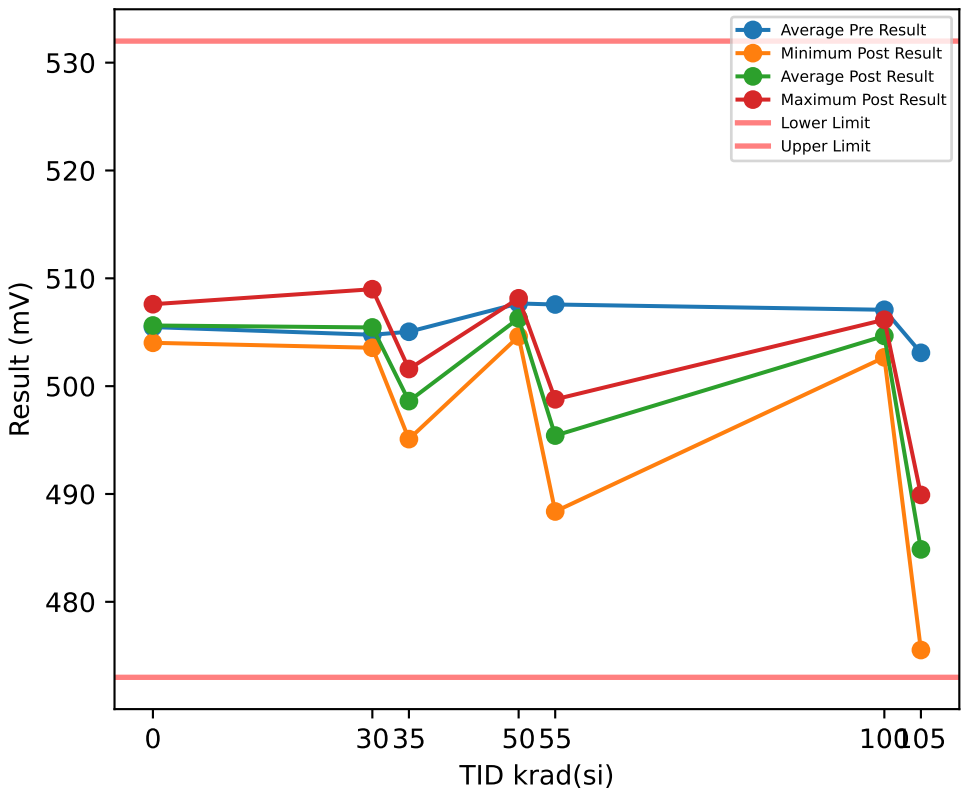
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	503.85	504.25	0.408
2	0	CU2	504.9	505.04	0.1357
3	0	CU3	507.71	507.66	-0.0459
11	30	Unbiased-30krad	503.26	503.78	0.5223
12	30	Unbiased-30krad	503.57	503.6	0.031
13	30	Unbiased-30krad	502.9	504.65	1.7441
14	30	Unbiased-30krad	505.8	506.21	0.4165
15	30	Unbiased-30krad	508.59	509.24	0.6451
16	35	Biased-30krad	507.83	501.64	-6.1909
17	35	Biased-30krad	503.75	495.31	-8.4331
18	35	Biased-30krad	506.36	499.95	-6.4069
19	35	Biased-30krad	503.9	497.64	-6.2597
20	35	Biased-30krad	503.48	498.53	-4.9485
30	50	Unbiased-50krad	504.88	504.55	-0.326
31	50	Unbiased-50krad	508.84	505.89	-2.9451
32	50	Unbiased-50krad	508.42	508.37	-0.0538
33	50	Unbiased-50krad	507.6	506.24	-1.3622
34	50	Unbiased-50krad	508.97	507.22	-1.7516
40	55	Biased-50krad	507.6	496.61	-10.993
41	55	Biased-50krad	507.23	488.48	-18.742
42	55	Biased-50krad	507.06	495.69	-11.372
43	55	Biased-50krad	510	497.91	-12.092
44	55	Biased-50krad	506.99	498.93	-8.0595
45	100	Unbiased-100krad	508.43	504.84	-3.5975
46	100	Unbiased-100krad	505.87	503.94	-1.9255
47	100	Unbiased-100krad	506.3	502.8	-3.4988
48	100	Unbiased-100krad	509.11	506.25	-2.8575
49	100	Unbiased-100krad	506.56	506.33	-0.2261
50	105	Biased-100krad	504.78	490.14	-14.644
51	105	Biased-100krad	501.58	475.59	-25.993
52	105	Biased-100krad	502.57	487.23	-15.338
53	105	Biased-100krad	501.35	483.42	-17.928
54	105	Biased-100krad	505.7	488.35	-17.358

Test Statistics (mV)

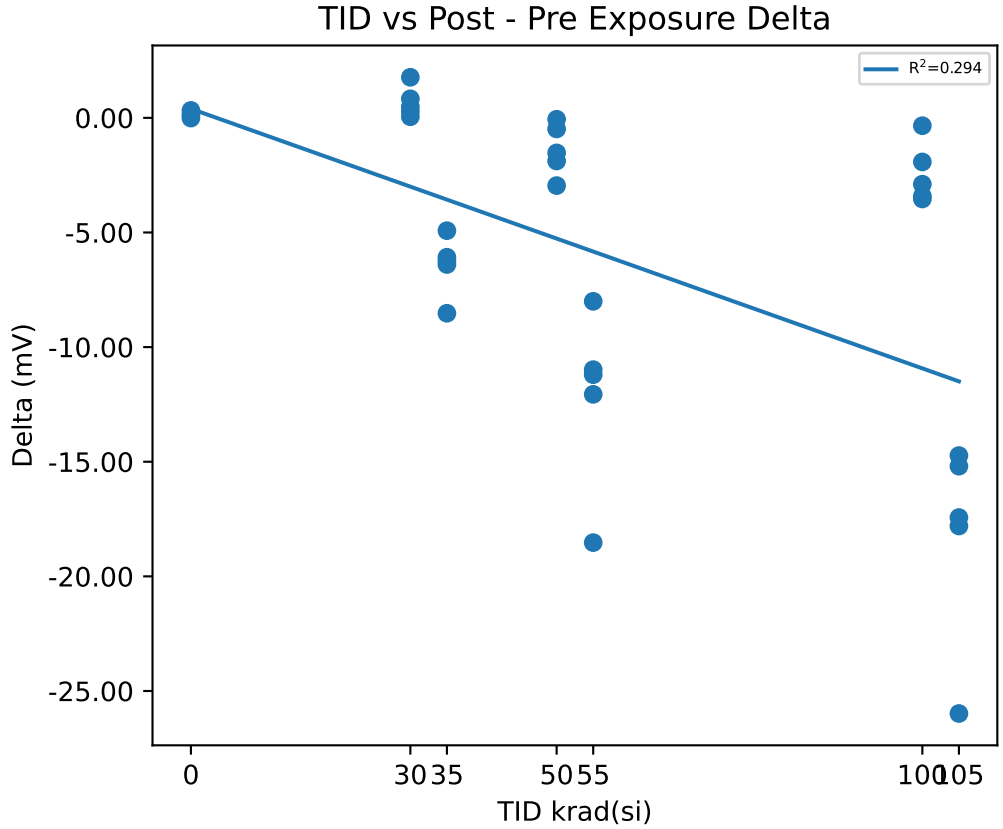
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	503.85	505.48	507.71	1.9943	504.25	505.65	507.66	1.7833	-0.0459	0.16593	0.408	0.22846
30	502.9	504.82	508.59	2.3902	503.6	505.5	509.24	2.3323	0.031	0.6718	1.7441	0.64201
35	503.48	505.06	507.83	1.9301	495.31	498.62	501.64	2.3859	-8.4331	-6.4478	-4.9485	1.2542
50	504.88	507.74	508.97	1.6869	504.55	506.45	508.37	1.4332	-2.9451	-1.2877	-0.0538	1.1635
55	506.99	507.78	510	1.265	488.48	495.52	498.93	4.1237	-18.742	-12.252	-8.0595	3.9398
100	505.87	507.25	509.11	1.4271	502.8	504.83	506.33	1.5142	-3.5975	-2.4211	-0.2261	1.3964
105	501.35	503.2	505.7	1.9518	475.59	484.94	490.14	5.7817	-25.993	-18.252	-14.644	4.5369

Device Test: 34.8 _Enable|FallingThreshold/EN4/7/7///90.9/634//0///@EN_VTH_FALLING

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 473.0, Upper Limit = 532.0 (mV))

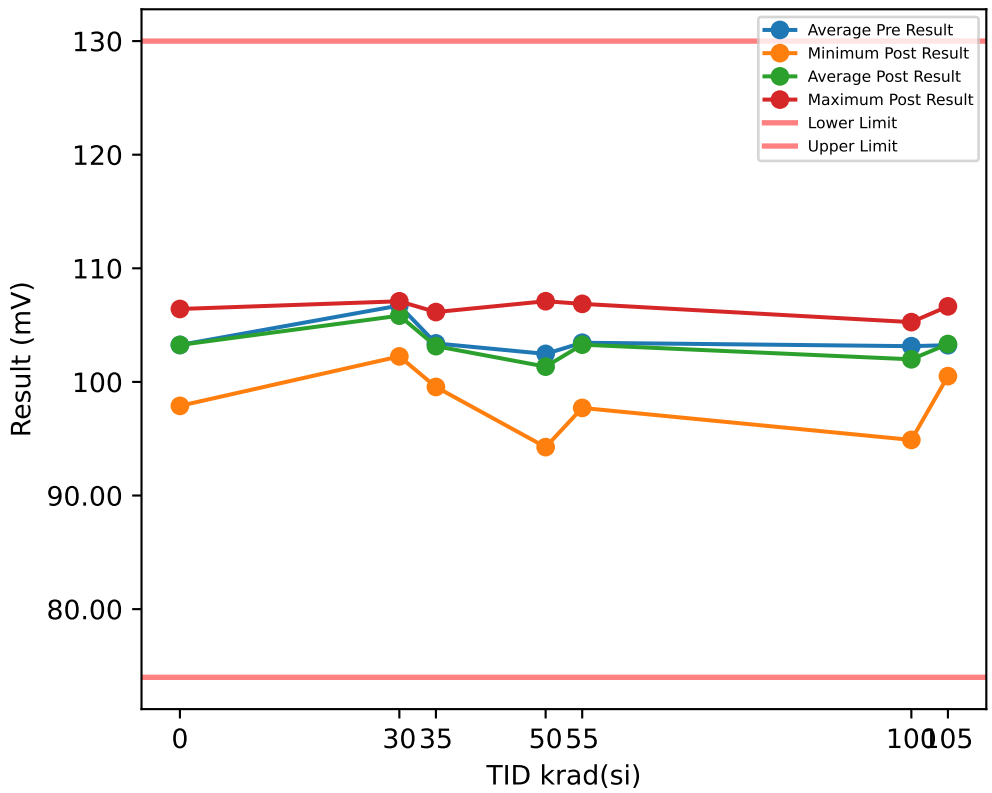
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	503.7	504.02	0.3248
2	0	CU2	505.12	505.26	0.1379
3	0	CU3	507.61	507.6	-0.0095
11	30	Unbiased-30krad	503.1	503.93	0.8301
12	30	Unbiased-30krad	503.51	503.56	0.0487
13	30	Unbiased-30krad	503.01	504.78	1.7692
14	30	Unbiased-30krad	505.69	505.96	0.2712
15	30	Unbiased-30krad	508.51	508.99	0.4811
16	35	Biased-30krad	507.67	501.59	-6.0794
17	35	Biased-30krad	503.61	495.09	-8.5238
18	35	Biased-30krad	506.44	500.2	-6.2352
19	35	Biased-30krad	504.13	497.74	-6.3966
20	35	Biased-30krad	503.37	498.45	-4.9213
30	50	Unbiased-50krad	505.1	504.61	-0.4834
31	50	Unbiased-50krad	508.69	505.74	-2.9545
32	50	Unbiased-50krad	508.21	508.15	-0.0624
33	50	Unbiased-50krad	507.53	506.01	-1.5272
34	50	Unbiased-50krad	508.81	506.93	-1.8813
40	55	Biased-50krad	507.53	496.55	-10.983
41	55	Biased-50krad	506.91	488.38	-18.528
42	55	Biased-50krad	506.82	495.61	-11.203
43	55	Biased-50krad	509.83	497.77	-12.06
44	55	Biased-50krad	506.78	498.78	-8.0028
45	100	Unbiased-100krad	508.23	504.69	-3.5393
46	100	Unbiased-100krad	505.71	503.78	-1.9231
47	100	Unbiased-100krad	506.08	502.67	-3.4115
48	100	Unbiased-100krad	508.89	505.99	-2.8951
49	100	Unbiased-100krad	506.5	506.16	-0.3424
50	105	Biased-100krad	504.64	489.91	-14.73
51	105	Biased-100krad	501.51	475.53	-25.982
52	105	Biased-100krad	502.6	487.41	-15.194
53	105	Biased-100krad	501.12	483.32	-17.803
54	105	Biased-100krad	505.58	488.14	-17.434

Test Statistics (mV)

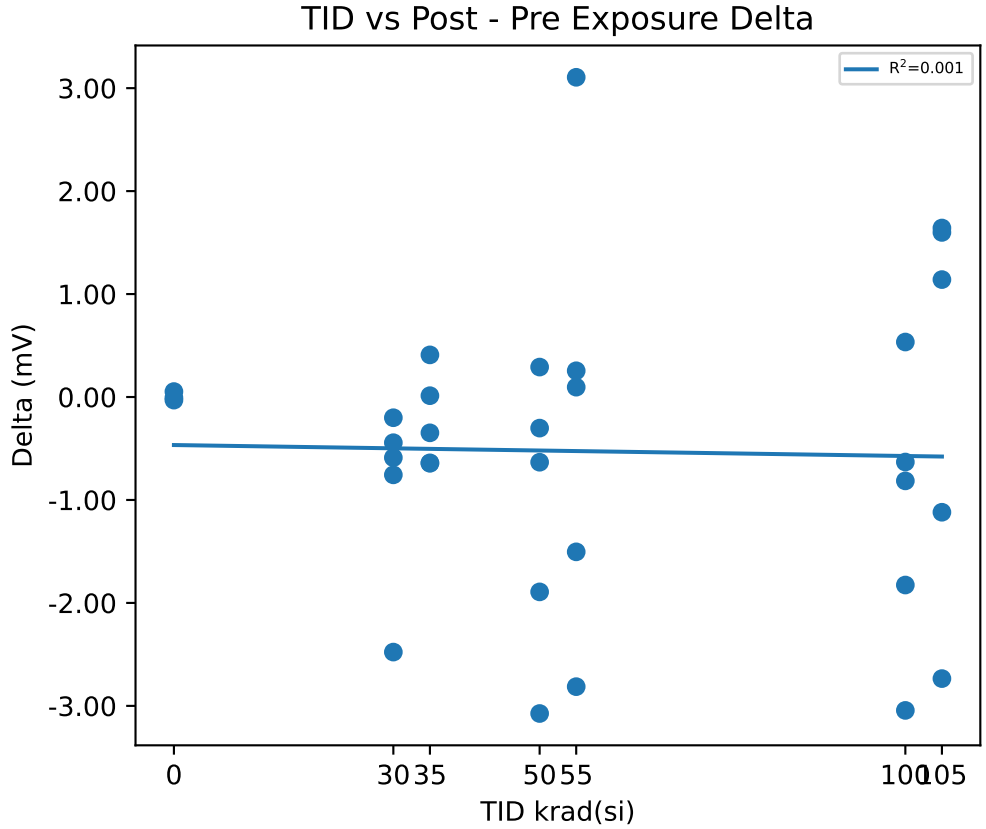
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	503.7	505.48	507.61	1.9792	504.02	505.63	507.6	1.8162	-0.0095	0.15107	0.3248	0.16754
30	503.01	504.76	508.51	2.3615	503.56	505.44	508.99	2.1871	0.0487	0.68006	1.7692	0.67344
35	503.37	505.04	507.67	1.9041	495.09	498.61	501.59	2.4799	-8.5238	-6.4313	-4.9213	1.306
50	505.1	507.67	508.81	1.5227	504.61	506.29	508.15	1.327	-2.9545	-1.3818	-0.0624	1.1502
55	506.78	507.57	509.83	1.2973	488.38	495.42	498.78	4.1138	-18.528	-12.155	-8.0028	3.8776
100	505.71	507.08	508.89	1.3969	502.67	504.66	506.16	1.479	-3.5393	-2.4223	-0.3424	1.3252
105	501.12	503.09	505.58	1.9492	475.53	484.86	489.91	5.7491	-25.982	-18.229	-14.73	4.5381

Device Test: 34.9 _Enable|Hys/EN1/7/7///90.9/634//0///@EN_VTH_HYST

TID vs Result Stats



TID vs Post - Pre Exposure Delta



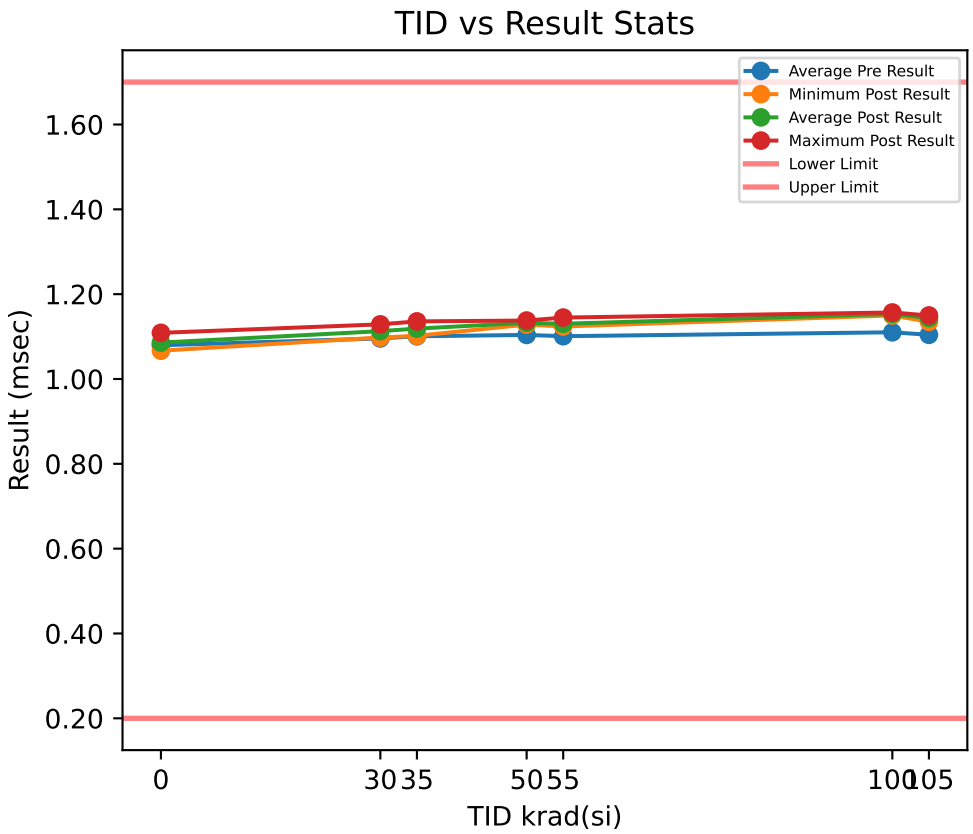
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

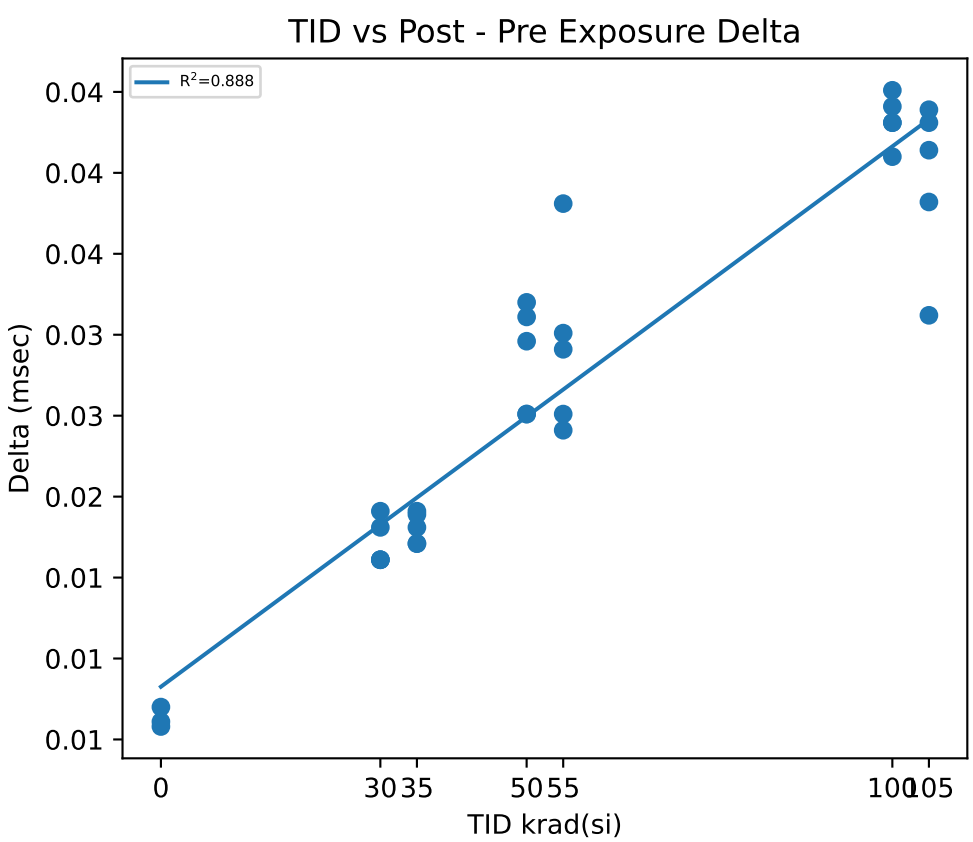
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	106.45	106.42	-0.0302
2	0	CU2	97.839	97.892	0.053
3	0	CU3	105.46	105.45	-0.0067
11	30	Unbiased-30krad	106.8	106.6	-0.2012
12	30	Unbiased-30krad	104.72	102.25	-2.4775
13	30	Unbiased-30krad	107.12	106.53	-0.5889
14	30	Unbiased-30krad	107.43	106.67	-0.756
15	30	Unbiased-30krad	107.54	107.1	-0.4438
16	35	Biased-30krad	103.99	103.64	-0.3479
17	35	Biased-30krad	106.14	106.15	0.0129
18	35	Biased-30krad	100.64	101.05	0.4092
19	35	Biased-30krad	100.2	99.557	-0.6436
20	35	Biased-30krad	105.98	105.34	-0.6396
30	50	Unbiased-50krad	94.894	94.261	-0.6334
31	50	Unbiased-50krad	103.36	100.28	-3.0741
32	50	Unbiased-50krad	107.41	107.1	-0.302
33	50	Unbiased-50krad	104.33	104.62	0.2909
34	50	Unbiased-50krad	102.36	100.46	-1.8928
40	55	Biased-50krad	104.21	102.71	-1.5039
41	55	Biased-50krad	97.616	97.712	0.0957
42	55	Biased-50krad	106.16	103.34	-2.8133
43	55	Biased-50krad	106.62	106.87	0.2549
44	55	Biased-50krad	102.65	105.75	3.1055
45	100	Unbiased-100krad	104.2	102.38	-1.8261
46	100	Unbiased-100krad	97.938	94.894	-3.044
47	100	Unbiased-100krad	102.02	102.56	0.5342
48	100	Unbiased-100krad	105.49	104.86	-0.6315
49	100	Unbiased-100krad	106.08	105.26	-0.8146
50	105	Biased-100krad	105.51	106.65	1.1406
51	105	Biased-100krad	103.23	102.11	-1.1192
52	105	Biased-100krad	101.08	102.68	1.5987
53	105	Biased-100krad	103.1	104.74	1.6415
54	105	Biased-100krad	103.24	100.51	-2.735

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.839	103.25	106.45	4.7122	97.892	103.26	106.42	4.67	-0.0302	0.0053667	0.053	0.042892
30	104.72	106.72	107.54	1.1547	102.25	105.83	107.1	2.016	-2.4775	-0.89348	-0.2012	0.90861
35	100.2	103.39	106.14	2.8443	99.557	103.15	106.15	2.8004	-0.6436	-0.2418	0.4092	0.45266
50	94.894	102.47	107.41	4.6366	94.261	101.35	107.1	4.898	-3.0741	-1.1223	0.2909	1.3521
55	97.616	103.45	106.62	3.6266	97.712	103.28	106.87	3.5475	-2.8133	-0.17222	3.1055	2.2218
100	97.938	103.15	106.08	3.3016	94.894	101.99	105.26	4.1766	-3.044	-1.1564	0.5342	1.3474
105	101.08	103.23	105.51	1.5691	100.51	103.34	106.65	2.393	-2.735	0.10532	1.6415	1.9512

Device Test: 35.1 _EnableDelay|EnRisingToSwRising/EN1/3/3///90.9/634//0///@T_ENABLE_DELAY_VIN





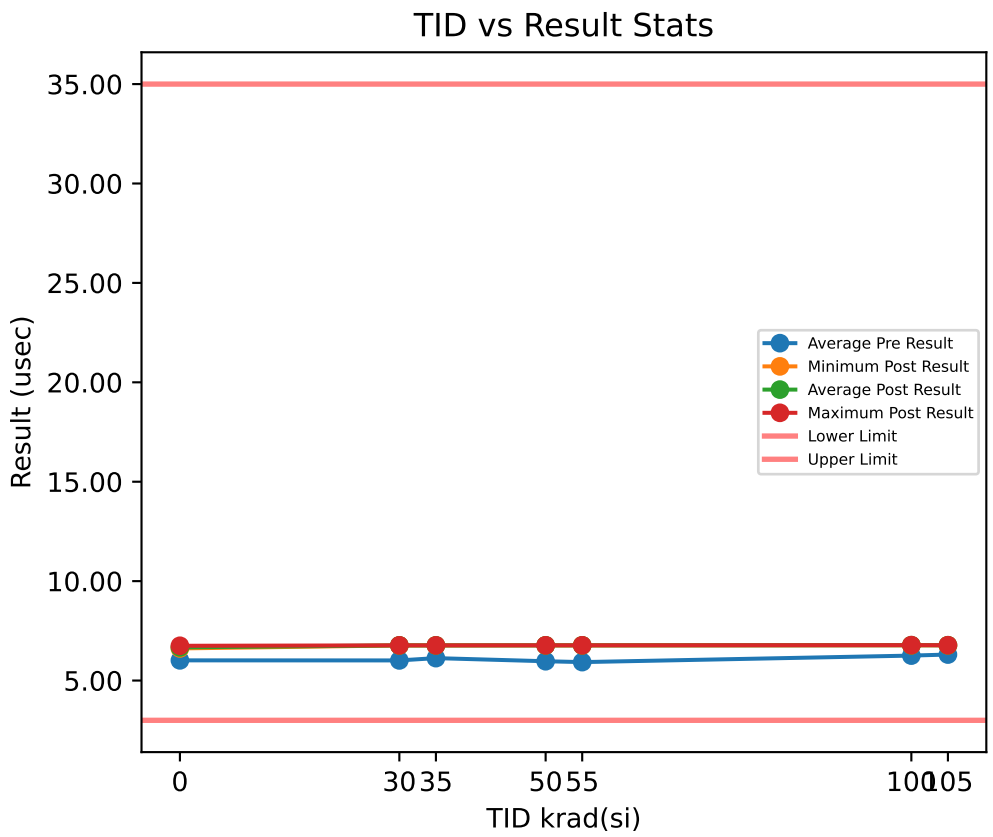
Test Results (Lower Limit = 0.2, Upper Limit = 1.7 (msec))

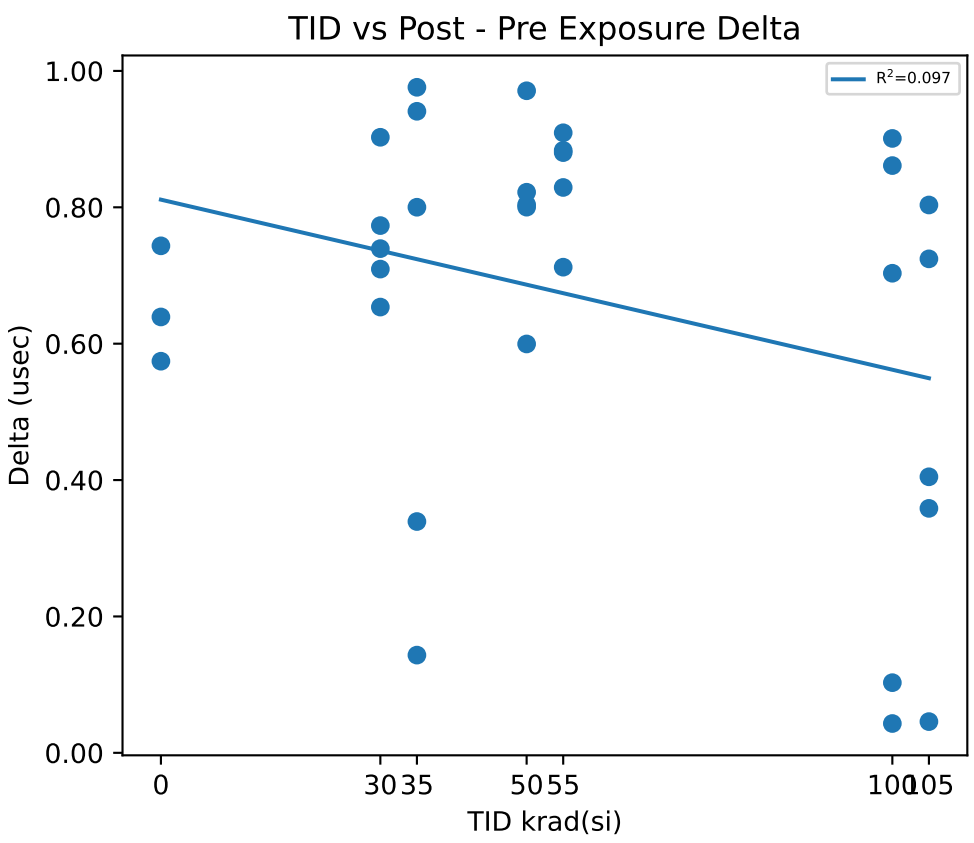
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0597	1.0667	0.007
2	0	CU2	1.1027	1.1088	0.0061
3	0	CU3	1.076	1.0818	0.0058
11	30	Unbiased-30krad	1.0957	1.1118	0.0161
12	30	Unbiased-30krad	1.1027	1.1188	0.0161
13	30	Unbiased-30krad	1.1097	1.1288	0.0191
14	30	Unbiased-30krad	1.0907	1.1068	0.0161
15	30	Unbiased-30krad	1.0797	1.0978	0.0181
16	35	Biased-30krad	1.0997	1.1186	0.0189
17	35	Biased-30krad	1.1037	1.1228	0.0191
18	35	Biased-30krad	1.0847	1.1018	0.0171
19	35	Biased-30krad	1.0977	1.1148	0.0171
20	35	Biased-30krad	1.1177	1.1358	0.0181
30	50	Unbiased-50krad	1.1127	1.1378	0.0251
31	50	Unbiased-50krad	1.1057	1.1308	0.0251
32	50	Unbiased-50krad	1.1057	1.1368	0.0311
33	50	Unbiased-50krad	1.0967	1.1287	0.032
34	50	Unbiased-50krad	1.0987	1.1283	0.0296
40	55	Biased-50krad	1.0997	1.1238	0.0241
41	55	Biased-50krad	1.0947	1.1238	0.0291
42	55	Biased-50krad	1.1067	1.1448	0.0381
43	55	Biased-50krad	1.0997	1.1298	0.0301
44	55	Biased-50krad	1.1037	1.1288	0.0251
45	100	Unbiased-100krad	1.1117	1.1568	0.0451
46	100	Unbiased-100krad	1.1067	1.1498	0.0431
47	100	Unbiased-100krad	1.1148	1.1558	0.041
48	100	Unbiased-100krad	1.1087	1.1518	0.0431
49	100	Unbiased-100krad	1.1087	1.1528	0.0441
50	105	Biased-100krad	1.0977	1.1416	0.0439
51	105	Biased-100krad	1.1036	1.1348	0.0312
52	105	Biased-100krad	1.1047	1.1478	0.0431
53	105	Biased-100krad	1.1116	1.1498	0.0382
54	105	Biased-100krad	1.1034	1.1448	0.0414

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0597	1.0795	1.1027	0.021709	1.0667	1.0858	1.1088	0.021328	0.0058	0.0063	0.007	0.0006245
30	1.0797	1.0957	1.1097	0.011467	1.0978	1.1128	1.1288	0.011769	0.0161	0.0171	0.0191	0.0014142
35	1.0847	1.1007	1.1177	0.011874	1.1018	1.1188	1.1358	0.012349	0.0171	0.01806	0.0191	0.00095289
50	1.0967	1.1039	1.1127	0.0063797	1.1283	1.1325	1.1378	0.0045152	0.0251	0.02858	0.032	0.0032904
55	1.0947	1.1009	1.1067	0.0045497	1.1238	1.1302	1.1448	0.0086197	0.0241	0.0293	0.0381	0.0055408
100	1.1067	1.1101	1.1148	0.0031673	1.1498	1.1534	1.1568	0.002881	0.041	0.04328	0.0451	0.0015205
105	1.0977	1.1042	1.1116	0.0049563	1.1348	1.1438	1.1498	0.0058913	0.0312	0.03956	0.0439	0.0051597

Device Test: 35.10 _EnableDelay|EnFallingToSwFalling/EN2/3/3///90.9/634//0///@T_DISABLE_DELAY





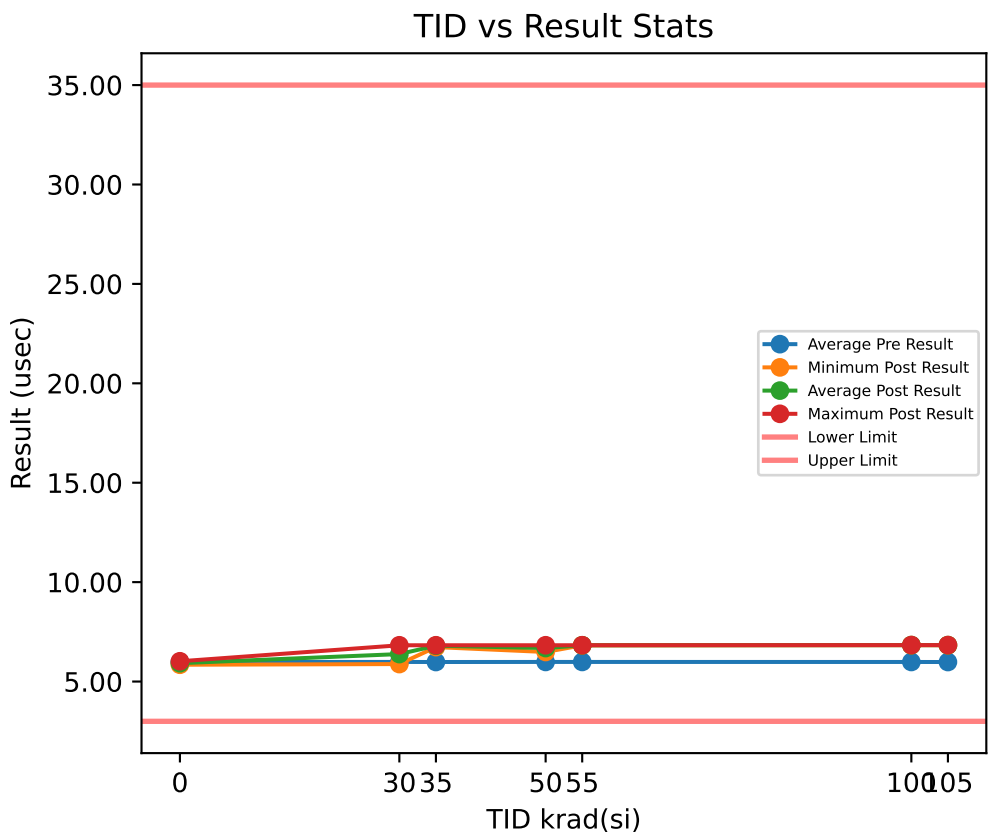
Test Results (Lower Limit = 3.0, Upper Limit = 35.0 (usec))

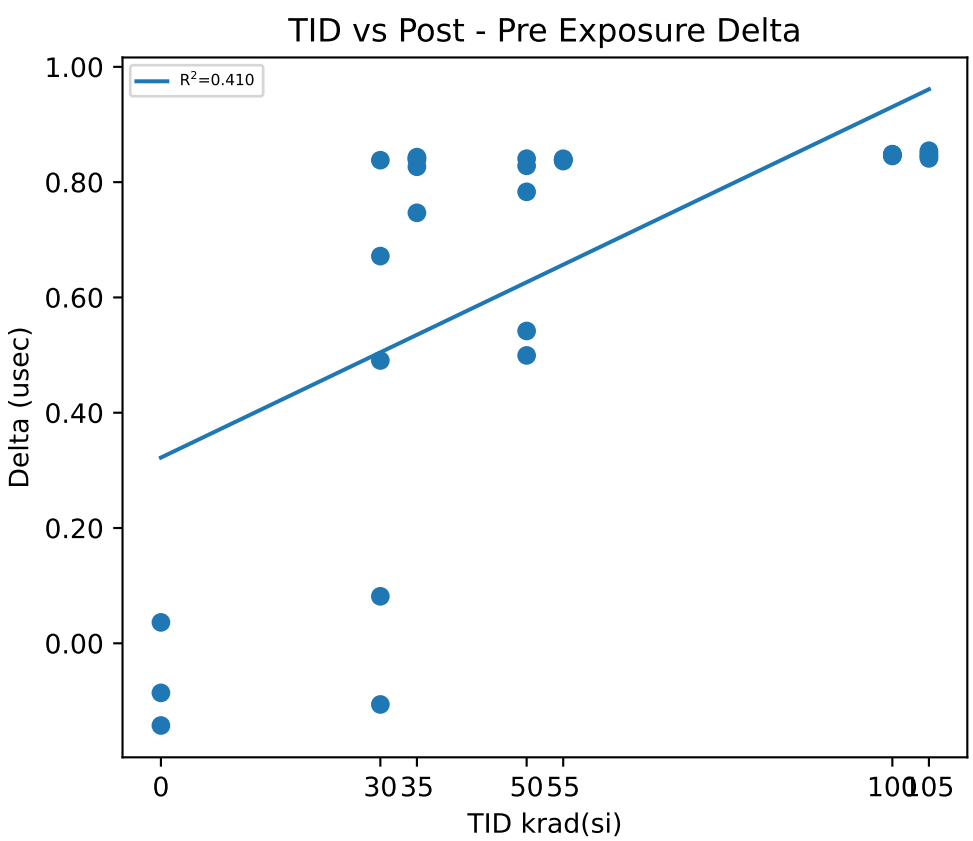
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8967	6.6402	0.7435
2	0	CU2	6.0406	6.6149	0.5743
3	0	CU3	6.109	6.7482	0.6392
11	30	Unbiased-30krad	6.0563	6.7657	0.7094
12	30	Unbiased-30krad	5.8643	6.767	0.9027
13	30	Unbiased-30krad	6.0267	6.7661	0.7394
14	30	Unbiased-30krad	6.1164	6.7701	0.6537
15	30	Unbiased-30krad	5.997	6.7702	0.7732
16	35	Biased-30krad	5.9682	6.7683	0.8001
17	35	Biased-30krad	6.428	6.7672	0.3392
18	35	Biased-30krad	5.7929	6.7689	0.976
19	35	Biased-30krad	5.8256	6.7664	0.9408
20	35	Biased-30krad	6.6235	6.7668	0.1433
30	50	Unbiased-50krad	5.7987	6.7696	0.9709
31	50	Unbiased-50krad	5.9644	6.7683	0.8039
32	50	Unbiased-50krad	6.1724	6.772	0.5996
33	50	Unbiased-50krad	5.9698	6.77	0.8002
34	50	Unbiased-50krad	5.9487	6.7708	0.8221
40	55	Biased-50krad	5.8882	6.7684	0.8802
41	55	Biased-50krad	5.9416	6.7707	0.8291
42	55	Biased-50krad	5.8866	6.7701	0.8835
43	55	Biased-50krad	6.0592	6.7714	0.7122
44	55	Biased-50krad	5.8612	6.7705	0.9093
45	100	Unbiased-100krad	5.873	6.774	0.901
46	100	Unbiased-100krad	5.915	6.7762	0.8612
47	100	Unbiased-100krad	6.0746	6.7779	0.7033
48	100	Unbiased-100krad	6.735	6.778	0.043
49	100	Unbiased-100krad	6.6773	6.7802	0.1029
50	105	Biased-100krad	5.9713	6.7747	0.8034
51	105	Biased-100krad	6.7307	6.7765	0.0458
52	105	Biased-100krad	6.3705	6.7753	0.4048
53	105	Biased-100krad	6.0478	6.7722	0.7244
54	105	Biased-100krad	6.4173	6.7758	0.3585

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8967	6.0154	6.109	0.10836	6.6149	6.6678	6.7482	0.070797	0.5743	0.65233	0.7435	0.085361
30	5.8643	6.0121	6.1164	0.093699	6.7657	6.7678	6.7702	0.0021788	0.6537	0.75568	0.9027	0.093178
35	5.7929	6.1276	6.6235	0.37576	6.7664	6.7675	6.7689	0.0010474	0.1433	0.63988	0.976	0.37623
50	5.7987	5.9708	6.1724	0.13303	6.7683	6.7701	6.772	0.0013777	0.5996	0.79934	0.9709	0.13216
55	5.8612	5.9274	6.0592	0.079304	6.7684	6.7702	6.7714	0.0011212	0.7122	0.84286	0.9093	0.078615
100	5.873	6.255	6.735	0.41917	6.774	6.7773	6.7802	0.0023104	0.043	0.52228	0.901	0.41733
105	5.9713	6.3075	6.7307	0.30643	6.7722	6.7749	6.7765	0.0016477	0.0458	0.46738	0.8034	0.30515

Device Test: 35.11 _EnableDelay|EnFallingToSwFalling/EN3/3/3///90.9/634//0///@T_DISABLE_DELAY





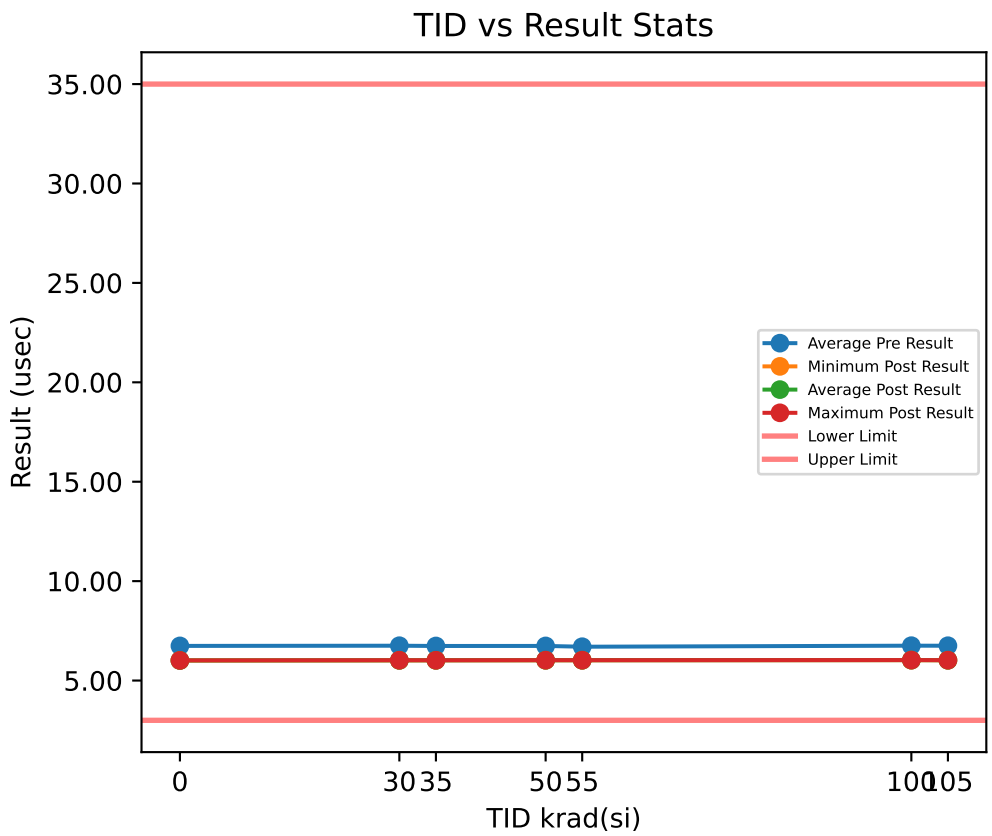
Test Results (Lower Limit = 3.0, Upper Limit = 35.0 (usec))

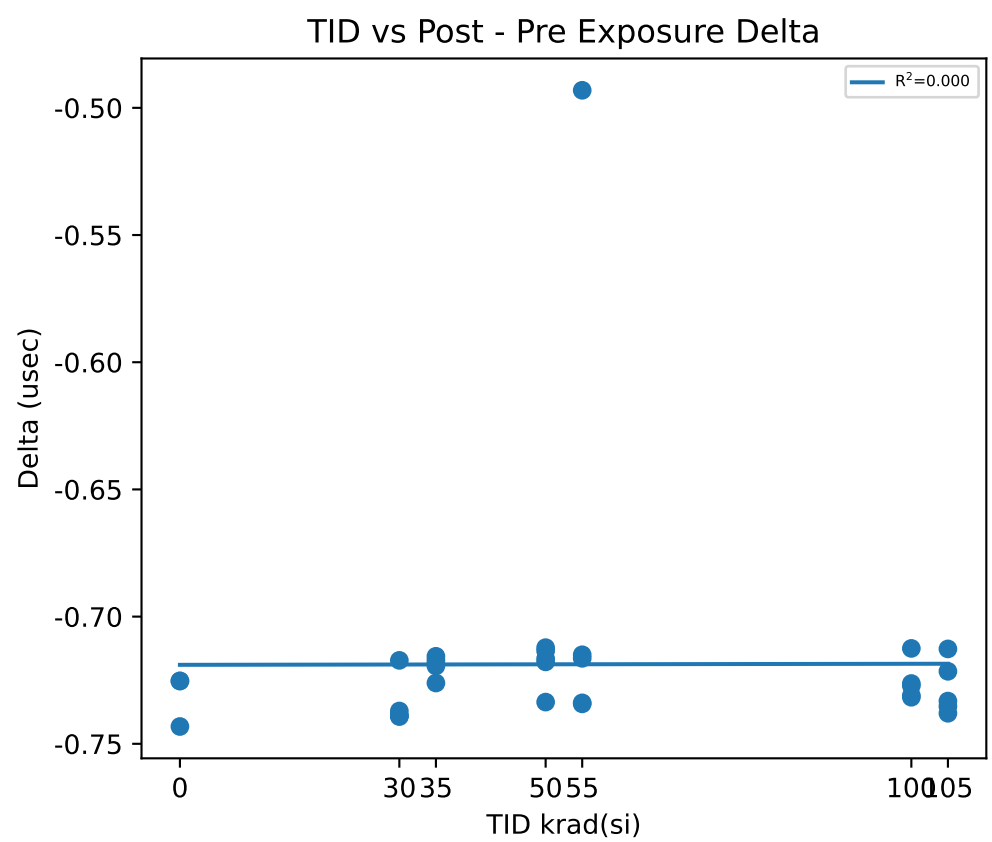
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9882	5.9022	-0.086
2	0	CU2	5.9832	6.0195	0.0363
3	0	CU3	5.9875	5.8449	-0.1426
11	30	Unbiased-30krad	5.9842	6.4748	0.4906
12	30	Unbiased-30krad	5.9859	6.824	0.8381
13	30	Unbiased-30krad	5.9887	6.6604	0.6717
14	30	Unbiased-30krad	5.9881	6.0696	0.0815
15	30	Unbiased-30krad	5.9852	5.8791	-0.1061
16	35	Biased-30krad	5.9809	6.8225	0.8416
17	35	Biased-30krad	5.9856	6.7324	0.7468
18	35	Biased-30krad	5.9863	6.825	0.8387
19	35	Biased-30krad	5.9772	6.8206	0.8434
20	35	Biased-30krad	5.9834	6.8101	0.8267
30	50	Unbiased-50krad	5.9847	6.8254	0.8407
31	50	Unbiased-50krad	5.9847	6.7679	0.7832
32	50	Unbiased-50krad	5.9873	6.4867	0.4994
33	50	Unbiased-50krad	5.9866	6.5284	0.5418
34	50	Unbiased-50krad	5.9876	6.8159	0.8283
40	55	Biased-50krad	5.9856	6.8221	0.8365
41	55	Biased-50krad	5.9862	6.8252	0.839
42	55	Biased-50krad	5.9878	6.8259	0.8381
43	55	Biased-50krad	5.9846	6.8252	0.8406
44	55	Biased-50krad	5.9851	6.8245	0.8394
45	100	Unbiased-100krad	5.985	6.8304	0.8454
46	100	Unbiased-100krad	5.9832	6.8314	0.8482
47	100	Unbiased-100krad	5.9859	6.8326	0.8467
48	100	Unbiased-100krad	5.9848	6.8309	0.8461
49	100	Unbiased-100krad	5.9838	6.8324	0.8486
50	105	Biased-100krad	5.9866	6.8278	0.8412
51	105	Biased-100krad	5.9759	6.8304	0.8545
52	105	Biased-100krad	5.9812	6.8323	0.8511
53	105	Biased-100krad	5.9822	6.8289	0.8467
54	105	Biased-100krad	5.985	6.8295	0.8445

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9832	5.9863	5.9882	0.0027074	5.8449	5.9222	6.0195	0.089002	-0.1426	-0.0641	0.0363	0.091439
30	5.9842	5.9864	5.9887	0.0019176	5.8791	6.3816	6.824	0.39749	-0.1061	0.39516	0.8381	0.39731
35	5.9772	5.9827	5.9863	0.0037198	6.7324	6.8021	6.825	0.039386	0.7468	0.81944	0.8434	0.041126
50	5.9847	5.9862	5.9876	0.0013989	6.4867	6.6849	6.8254	0.16399	0.4994	0.69868	0.8407	0.16465
55	5.9846	5.9859	5.9878	0.0012361	6.8221	6.8246	6.8259	0.0014721	0.8365	0.83872	0.8406	0.001532
100	5.9832	5.9845	5.9859	0.0010574	6.8304	6.8315	6.8326	0.00094763	0.8454	0.847	0.8486	0.0013657
105	5.9759	5.9822	5.9866	0.0041197	6.8278	6.8298	6.8323	0.0016962	0.8412	0.8476	0.8545	0.0052735

Device Test: 35.12 _EnableDelay|EnFallingToSwFalling/EN4/3/3///90.9/634//0///@T_DISABLE_DELAY





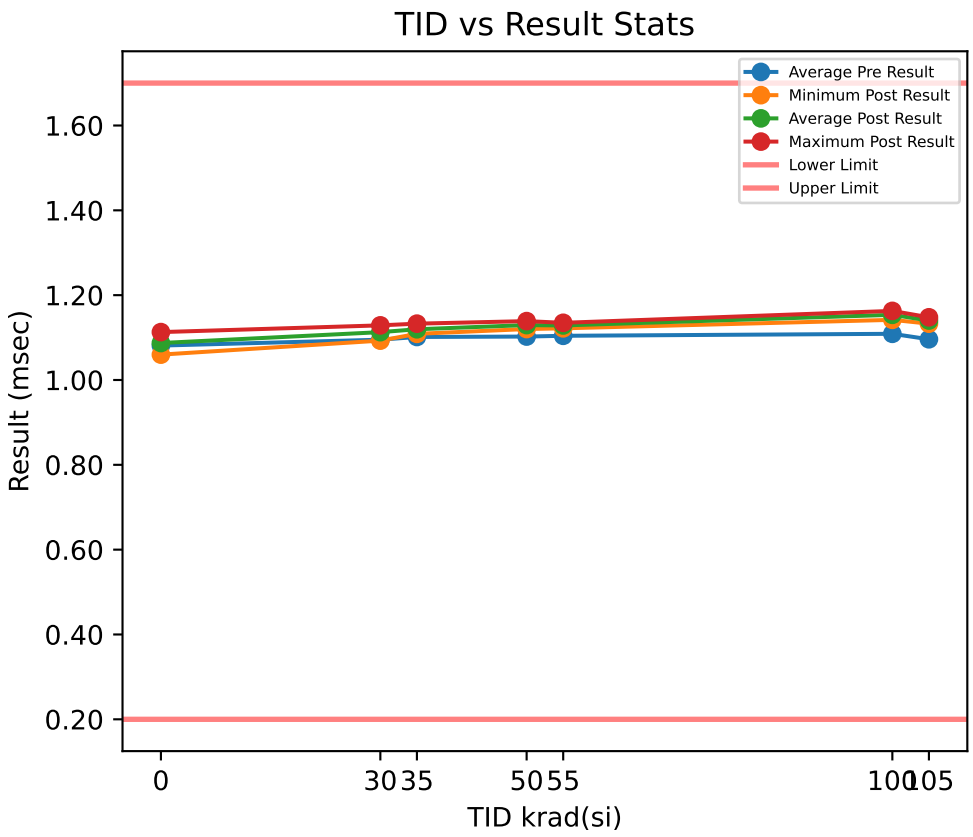
Test Results (Lower Limit = 3.0, Upper Limit = 35.0 (usec))

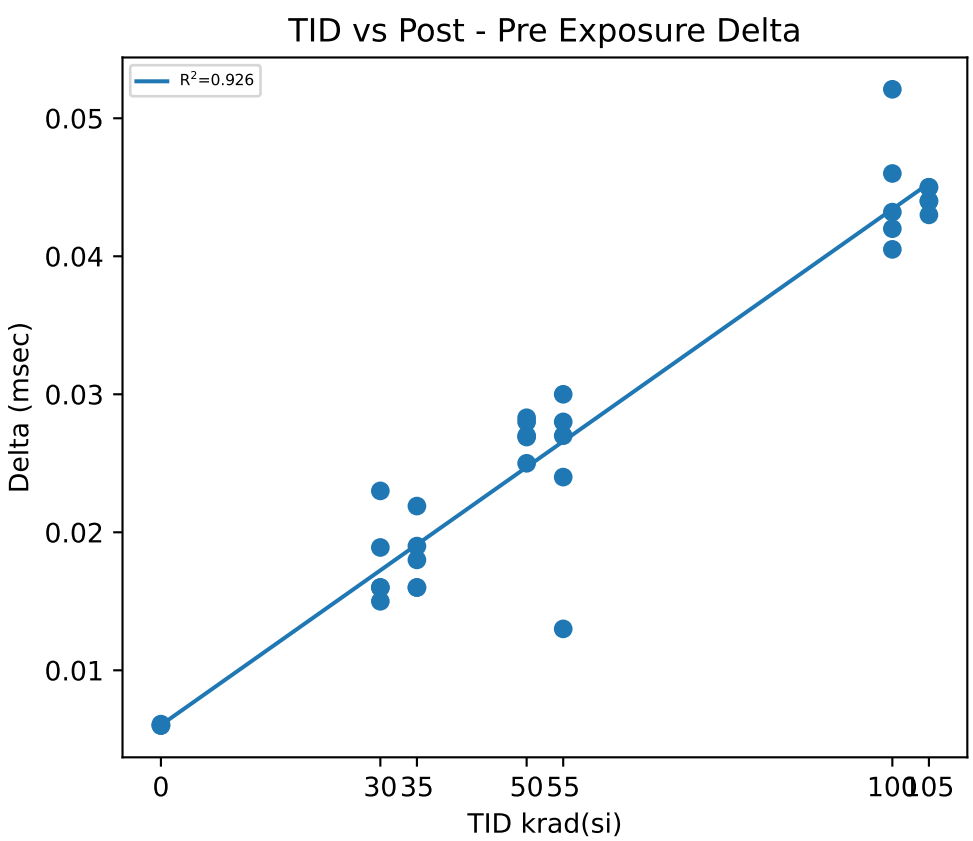
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.7346	6.0093	-0.7253
2	0	CU2	6.7523	6.0091	-0.7432
3	0	CU3	6.7391	6.0138	-0.7253
11	30	Unbiased-30krad	6.7544	6.0155	-0.7389
12	30	Unbiased-30krad	6.7397	6.0225	-0.7172
13	30	Unbiased-30krad	6.7557	6.0167	-0.739
14	30	Unbiased-30krad	6.7552	6.0159	-0.7393
15	30	Unbiased-30krad	6.7547	6.0176	-0.7371
16	35	Biased-30krad	6.7353	6.0181	-0.7172
17	35	Biased-30krad	6.7359	6.0203	-0.7156
18	35	Biased-30krad	6.7459	6.0198	-0.7261
19	35	Biased-30krad	6.7372	6.0186	-0.7186
20	35	Biased-30krad	6.7385	6.0191	-0.7194
30	50	Unbiased-50krad	6.7368	6.0233	-0.7135
31	50	Unbiased-50krad	6.7544	6.0208	-0.7336
32	50	Unbiased-50krad	6.7378	6.0213	-0.7165
33	50	Unbiased-50krad	6.7374	6.0196	-0.7178
34	50	Unbiased-50krad	6.7374	6.0252	-0.7122
40	55	Biased-50krad	6.7558	6.0219	-0.7339
41	55	Biased-50krad	6.5156	6.0225	-0.4931
42	55	Biased-50krad	6.7387	6.0237	-0.715
43	55	Biased-50krad	6.7551	6.0208	-0.7343
44	55	Biased-50krad	6.7403	6.0239	-0.7164
45	100	Unbiased-100krad	6.7569	6.0252	-0.7317
46	100	Unbiased-100krad	6.7401	6.0276	-0.7125
47	100	Unbiased-100krad	6.7552	6.0289	-0.7263
48	100	Unbiased-100krad	6.7572	6.0262	-0.731
49	100	Unbiased-100krad	6.7576	6.0304	-0.7272
50	105	Biased-100krad	6.7374	6.0247	-0.7127
51	105	Biased-100krad	6.7557	6.0225	-0.7332
52	105	Biased-100krad	6.7443	6.0228	-0.7215
53	105	Biased-100krad	6.7571	6.0191	-0.738
54	105	Biased-100krad	6.76	6.0247	-0.7353

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7346	6.742	6.7523	0.0091995	6.0091	6.0107	6.0138	0.0026577	-0.7432	-0.73127	-0.7253	0.010335
30	6.7397	6.7519	6.7557	0.0068602	6.0155	6.0176	6.0225	0.0028334	-0.7393	-0.7343	-0.7172	0.0095982
35	6.7353	6.7386	6.7459	0.0042846	6.0181	6.0192	6.0203	0.00088713	-0.7261	-0.71938	-0.7156	0.0040252
50	6.7368	6.7408	6.7544	0.0076333	6.0196	6.022	6.0252	0.0022143	-0.7336	-0.71872	-0.7122	0.0086161
55	6.5156	6.7011	6.7558	0.10401	6.0208	6.0226	6.0239	0.0012876	-0.7343	-0.67854	-0.4931	0.10407
100	6.7401	6.7534	6.7576	0.007491	6.0252	6.0277	6.0304	0.0020756	-0.7317	-0.72574	-0.7125	0.007761
105	6.7374	6.7509	6.76	0.009619	6.0191	6.0228	6.0247	0.0022909	-0.738	-0.72814	-0.7127	0.010684

Device Test: 35.2 _EnableDelay|EnRisingToSwRising/EN2/3/3///90.9/634//0///@T_ENABLE_DELAY_VIN





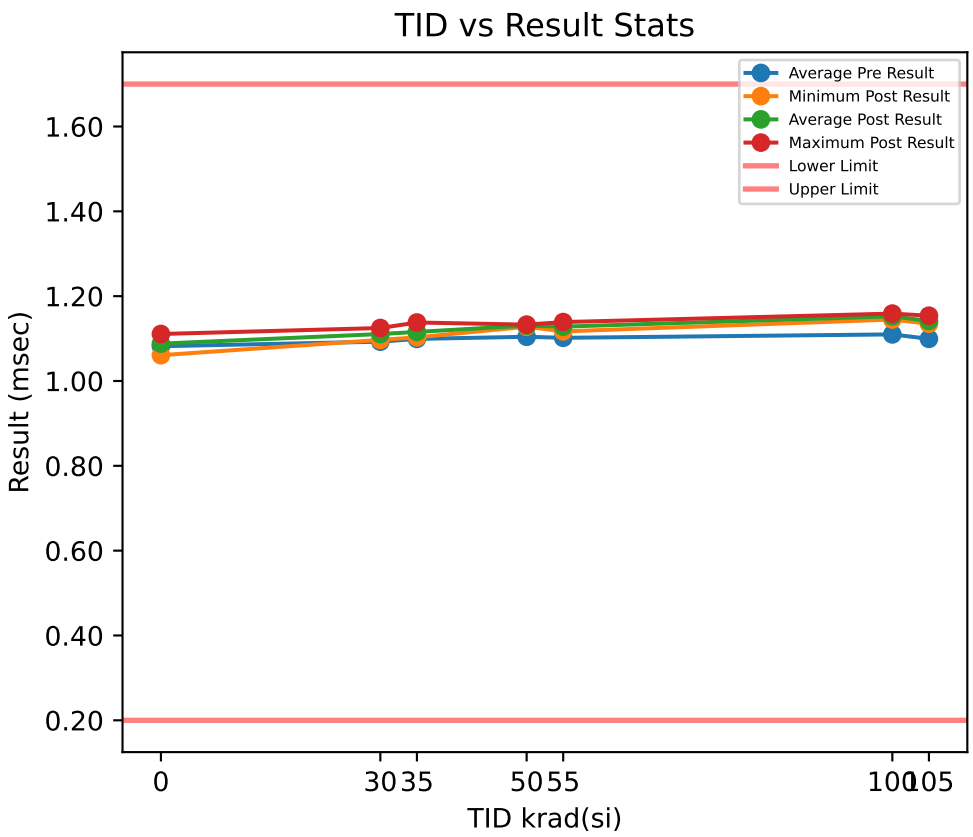
Test Results (Lower Limit = 0.2, Upper Limit = 1.7 (msec))

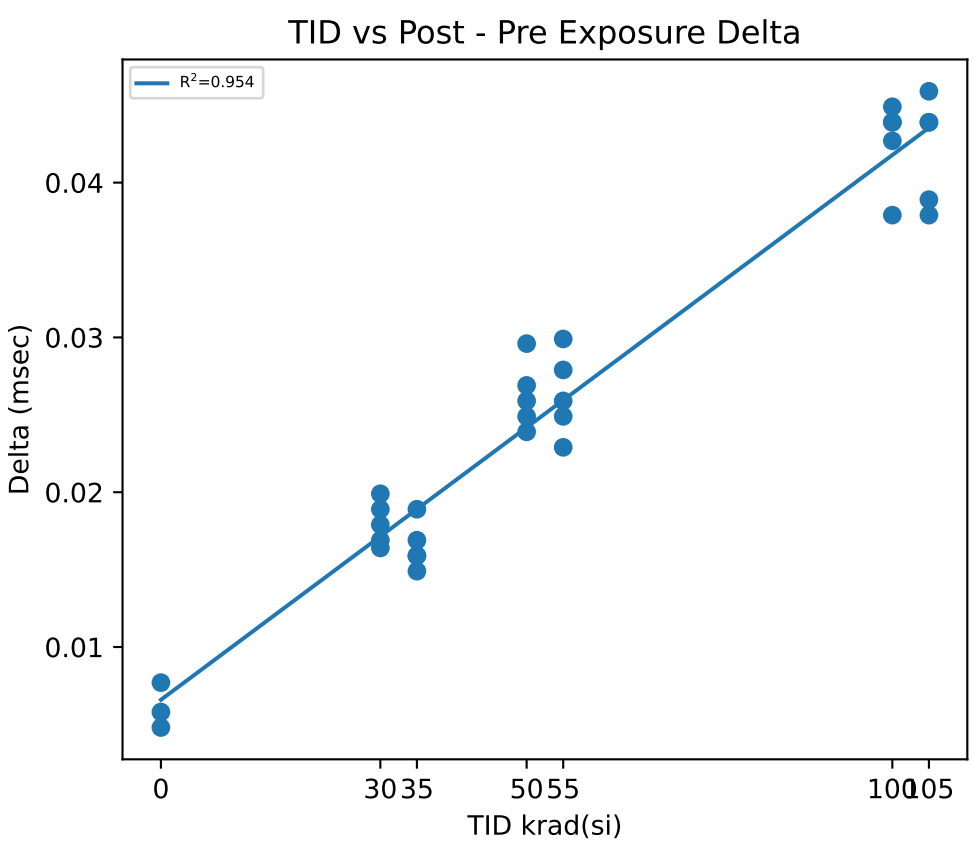
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0538	1.0598	0.006
2	0	CU2	1.1068	1.1129	0.0061
3	0	CU3	1.0828	1.0888	0.006
11	30	Unbiased-30krad	1.0959	1.1148	0.0189
12	30	Unbiased-30krad	1.0978	1.1138	0.016
13	30	Unbiased-30krad	1.1058	1.1288	0.023
14	30	Unbiased-30krad	1.0978	1.1138	0.016
15	30	Unbiased-30krad	1.0778	1.0928	0.015
16	35	Biased-30krad	1.0958	1.1118	0.016
17	35	Biased-30krad	1.1048	1.1238	0.019
18	35	Biased-30krad	1.0928	1.1088	0.016
19	35	Biased-30krad	1.0989	1.1208	0.0219
20	35	Biased-30krad	1.1148	1.1328	0.018
30	50	Unbiased-50krad	1.1108	1.1388	0.028
31	50	Unbiased-50krad	1.1069	1.1338	0.0269
32	50	Unbiased-50krad	1.1048	1.1298	0.025
33	50	Unbiased-50krad	1.0918	1.1201	0.0283
34	50	Unbiased-50krad	1.0978	1.1248	0.027
40	55	Biased-50krad	1.0948	1.1218	0.027
41	55	Biased-50krad	1.1108	1.1348	0.024
42	55	Biased-50krad	1.1058	1.1338	0.028
43	55	Biased-50krad	1.1098	1.1228	0.013
44	55	Biased-50krad	1.0998	1.1298	0.03
45	100	Unbiased-100krad	1.1108	1.1629	0.0521
46	100	Unbiased-100krad	1.1013	1.1418	0.0405
47	100	Unbiased-100krad	1.1068	1.1488	0.042
48	100	Unbiased-100krad	1.1157	1.1589	0.0432
49	100	Unbiased-100krad	1.1098	1.1558	0.046
50	105	Biased-100krad	1.0878	1.1328	0.045
51	105	Biased-100krad	1.0948	1.1378	0.043
52	105	Biased-100krad	1.0978	1.1418	0.044
53	105	Biased-100krad	1.1028	1.1478	0.045
54	105	Biased-100krad	1.0968	1.1408	0.044

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0538	1.0811	1.1068	0.026539	1.0598	1.0872	1.1129	0.026588	0.006	0.0060333	0.0061	5.7735e-05
30	1.0778	1.095	1.1058	0.010356	1.0928	1.1128	1.1288	0.012865	0.015	0.01778	0.023	0.0032622
35	1.0928	1.1014	1.1148	0.008699	1.1088	1.1196	1.1328	0.0096281	0.016	0.01818	0.0219	0.0024519
50	1.0918	1.1024	1.1108	0.0075843	1.1201	1.1295	1.1388	0.0073402	0.025	0.02704	0.0283	0.0012934
55	1.0948	1.1042	1.1108	0.0068044	1.1218	1.1286	1.1348	0.0060581	0.013	0.0244	0.03	0.0067305
100	1.1013	1.1089	1.1157	0.005311	1.1418	1.1536	1.1629	0.0083918	0.0405	0.04476	0.0521	0.004572
105	1.0878	1.096	1.1028	0.0054498	1.1328	1.1402	1.1478	0.0055045	0.043	0.0442	0.045	0.00083666

Device Test: 35.3 _EnableDelay|EnRisingToSwRising/EN3/3/3///90.9/634//0///@T_ENABLE_DELAY_VIN





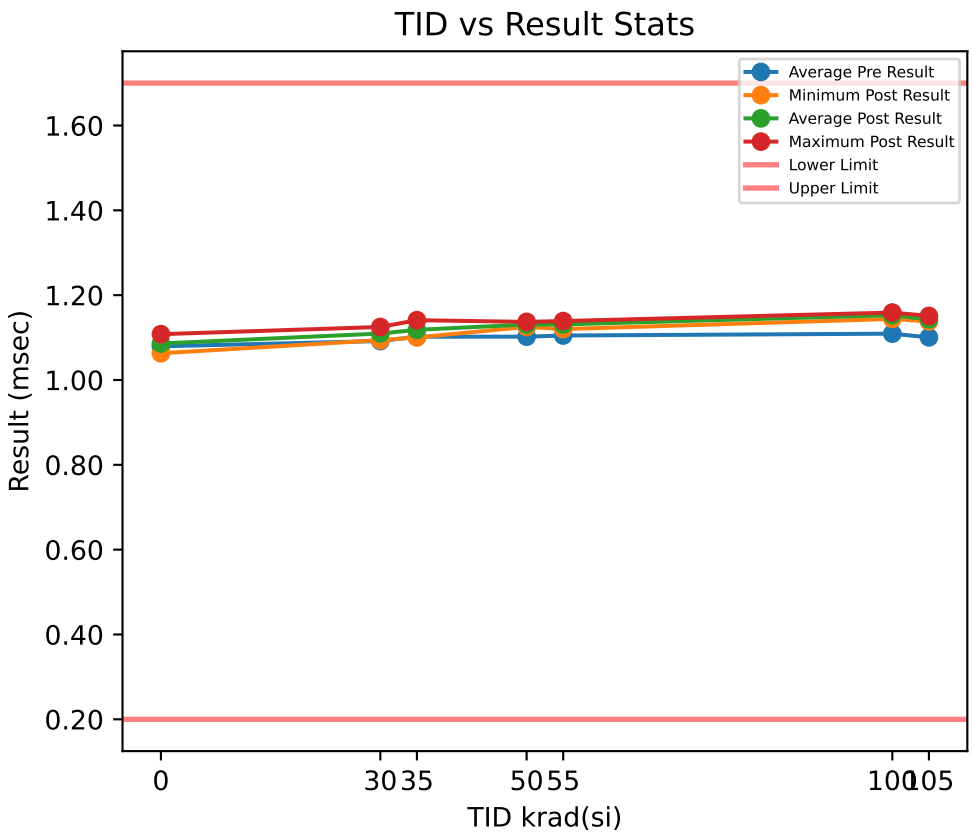
Test Results (Lower Limit = 0.2, Upper Limit = 1.7 (msec))

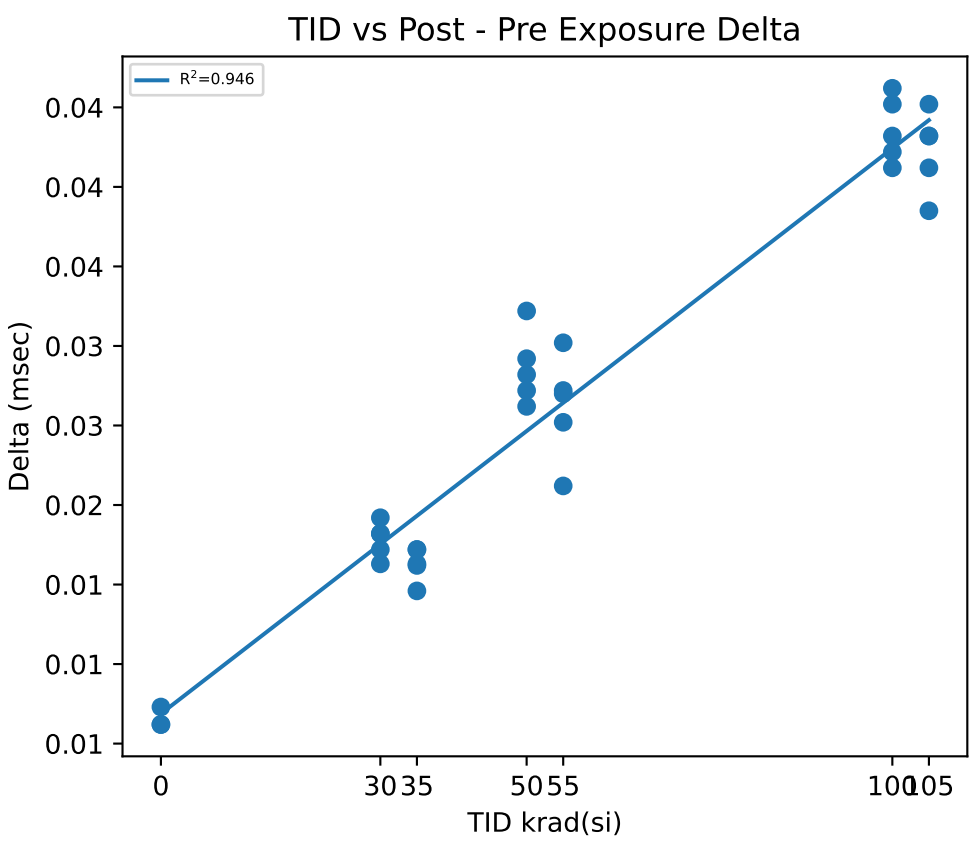
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.055	1.0608	0.0058
2	0	CU2	1.106	1.1108	0.0048
3	0	CU3	1.085	1.0927	0.0077
11	30	Unbiased-30krad	1.093	1.1099	0.0169
12	30	Unbiased-30krad	1.0935	1.1099	0.0164
13	30	Unbiased-30krad	1.105	1.1249	0.0199
14	30	Unbiased-30krad	1.093	1.1119	0.0189
15	30	Unbiased-30krad	1.079	1.0969	0.0179
16	35	Biased-30krad	1.097	1.1129	0.0159
17	35	Biased-30krad	1.098	1.1149	0.0169
18	35	Biased-30krad	1.095	1.1099	0.0149
19	35	Biased-30krad	1.084	1.1029	0.0189
20	35	Biased-30krad	1.122	1.1379	0.0159
30	50	Unbiased-50krad	1.108	1.1319	0.0239
31	50	Unbiased-50krad	1.103	1.1289	0.0259
32	50	Unbiased-50krad	1.106	1.1309	0.0249
33	50	Unbiased-50krad	1.0983	1.1279	0.0296
34	50	Unbiased-50krad	1.106	1.1329	0.0269
40	55	Biased-50krad	1.094	1.1169	0.0229
41	55	Biased-50krad	1.103	1.1279	0.0249
42	55	Biased-50krad	1.111	1.1389	0.0279
43	55	Biased-50krad	1.102	1.1319	0.0299
44	55	Biased-50krad	1.099	1.1249	0.0259
45	100	Unbiased-100krad	1.121	1.1589	0.0379
46	100	Unbiased-100krad	1.1022	1.1449	0.0427
47	100	Unbiased-100krad	1.111	1.1549	0.0439
48	100	Unbiased-100krad	1.11	1.1539	0.0439
49	100	Unbiased-100krad	1.105	1.1499	0.0449
50	105	Biased-100krad	1.1	1.1379	0.0379
51	105	Biased-100krad	1.096	1.1349	0.0389
52	105	Biased-100krad	1.095	1.1389	0.0439
53	105	Biased-100krad	1.108	1.1539	0.0459
54	105	Biased-100krad	1.098	1.1419	0.0439

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.055	1.082	1.106	0.025632	1.0608	1.0881	1.1108	0.025315	0.0048	0.0061	0.0077	0.0014731
30	1.079	1.0927	1.105	0.0092168	1.0969	1.1107	1.1249	0.0099348	0.0164	0.018	0.0199	0.0014318
35	1.084	1.0992	1.122	0.013918	1.1029	1.1157	1.1379	0.013217	0.0149	0.0165	0.0189	0.0015166
50	1.0983	1.1043	1.108	0.0037799	1.1279	1.1305	1.1329	0.0020736	0.0239	0.02624	0.0296	0.0021859
55	1.094	1.1018	1.111	0.0062209	1.1169	1.1281	1.1389	0.008167	0.0229	0.0263	0.0299	0.0027019
100	1.1022	1.1098	1.121	0.0072061	1.1449	1.1525	1.1589	0.0053198	0.0379	0.04266	0.0449	0.0027727
105	1.095	1.0994	1.108	0.0051769	1.1349	1.1415	1.1539	0.0073689	0.0379	0.0421	0.0459	0.0034928

Device Test: 35.4 _EnableDelay|EnRisingToSwRising/EN4/3/3///90.9/634//0///@T_ENABLE_DELAY_VIN





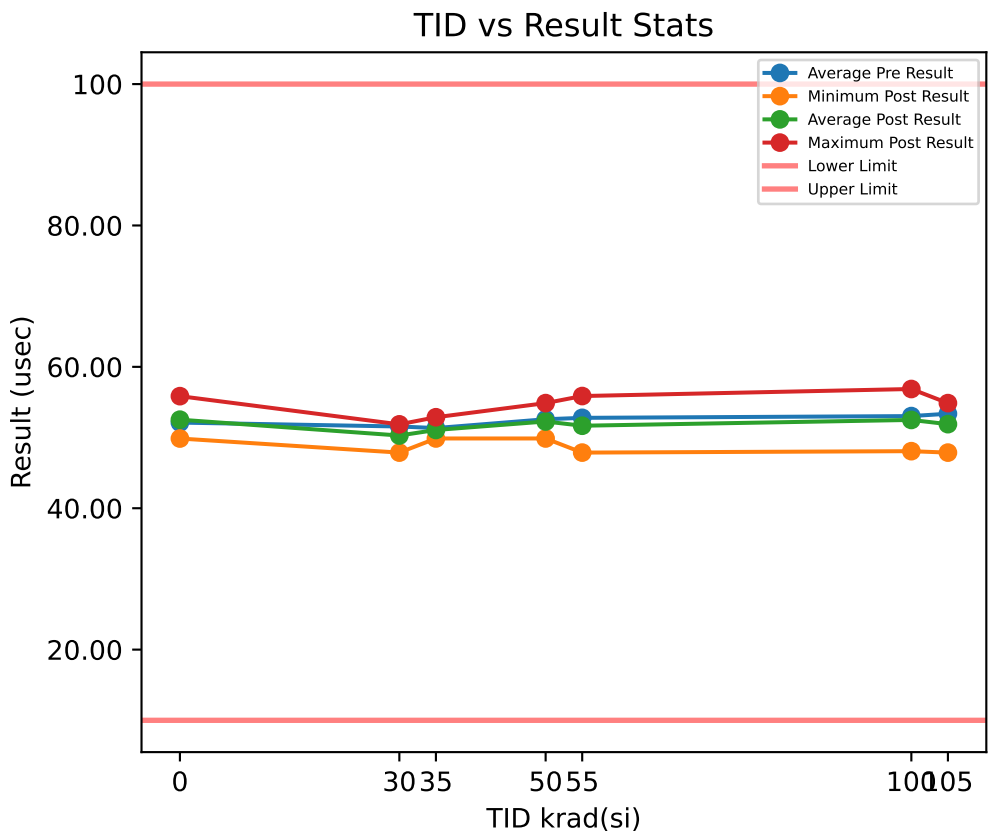
Test Results (Lower Limit = 0.2, Upper Limit = 1.7 (msec))

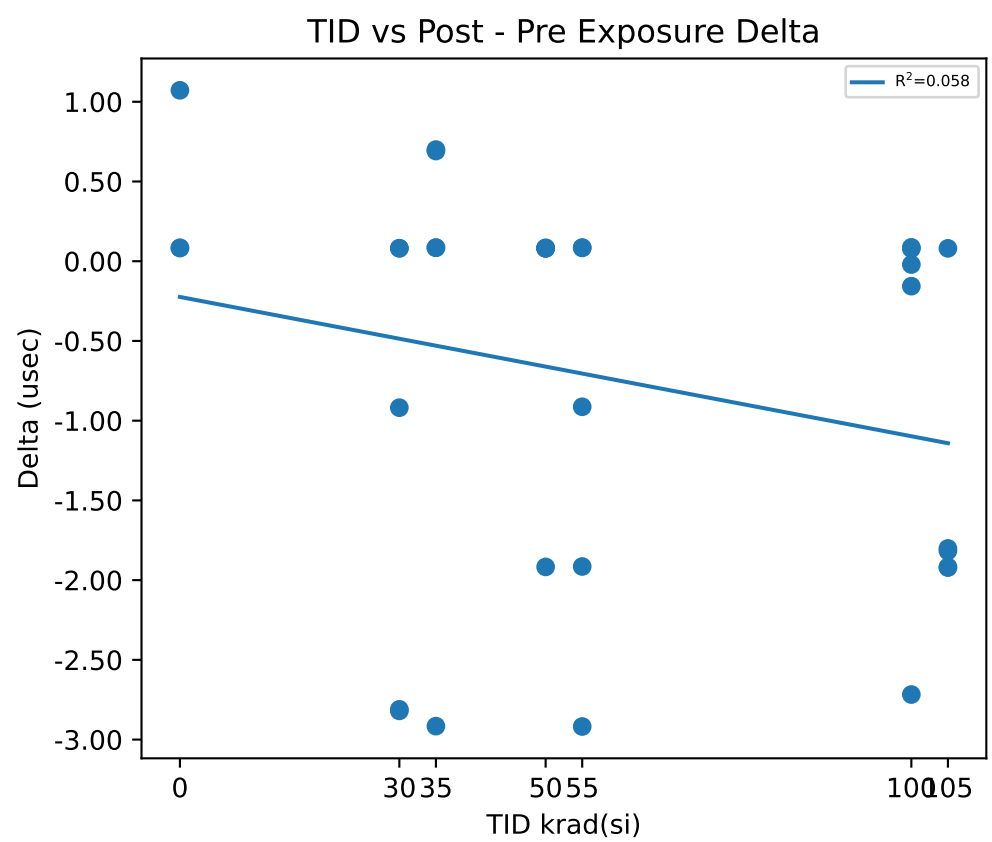
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0557	1.063	0.0073
2	0	CU2	1.1018	1.108	0.0062
3	0	CU3	1.0808	1.087	0.0062
11	30	Unbiased-30krad	1.0948	1.113	0.0182
12	30	Unbiased-30krad	1.0928	1.11	0.0172
13	30	Unbiased-30krad	1.1058	1.125	0.0192
14	30	Unbiased-30krad	1.0897	1.106	0.0163
15	30	Unbiased-30krad	1.0758	1.094	0.0182
16	35	Biased-30krad	1.0957	1.112	0.0163
17	35	Biased-30krad	1.1048	1.122	0.0172
18	35	Biased-30krad	1.0858	1.1004	0.0146
19	35	Biased-30krad	1.0988	1.116	0.0172
20	35	Biased-30krad	1.1248	1.141	0.0162
30	50	Unbiased-50krad	1.1088	1.137	0.0282
31	50	Unbiased-50krad	1.1048	1.132	0.0272
32	50	Unbiased-50krad	1.1068	1.133	0.0262
33	50	Unbiased-50krad	1.0928	1.125	0.0322
34	50	Unbiased-50krad	1.0978	1.127	0.0292
40	55	Biased-50krad	1.0988	1.12	0.0212
41	55	Biased-50krad	1.1058	1.133	0.0272
42	55	Biased-50krad	1.112	1.139	0.027
43	55	Biased-50krad	1.1048	1.135	0.0302
44	55	Biased-50krad	1.1028	1.128	0.0252
45	100	Unbiased-100krad	1.1168	1.158	0.0412
46	100	Unbiased-100krad	1.1058	1.149	0.0432
47	100	Unbiased-100krad	1.1018	1.144	0.0422
48	100	Unbiased-100krad	1.1138	1.159	0.0452
49	100	Unbiased-100krad	1.1078	1.154	0.0462
50	105	Biased-100krad	1.0968	1.138	0.0412
51	105	Biased-100krad	1.0995	1.138	0.0385
52	105	Biased-100krad	1.0988	1.144	0.0452
53	105	Biased-100krad	1.1078	1.151	0.0432
54	105	Biased-100krad	1.0998	1.143	0.0432

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0557	1.0794	1.1018	0.02308	1.063	1.086	1.108	0.022517	0.0062	0.0065667	0.0073	0.00063509
30	1.0758	1.0918	1.1058	0.010798	1.094	1.1096	1.125	0.011238	0.0163	0.01782	0.0192	0.0011054
35	1.0858	1.102	1.1248	0.014492	1.1004	1.1183	1.141	0.014953	0.0146	0.0163	0.0172	0.001063
50	1.0928	1.1022	1.1088	0.0066933	1.125	1.1308	1.137	0.0048166	0.0262	0.0286	0.0322	0.0023022
55	1.0988	1.1048	1.112	0.0048175	1.12	1.131	1.139	0.0073144	0.0212	0.02616	0.0302	0.0033027
100	1.1018	1.1092	1.1168	0.0060663	1.144	1.1528	1.159	0.0063008	0.0412	0.0436	0.0462	0.0020736
105	1.0968	1.1005	1.1078	0.0042235	1.138	1.1428	1.151	0.0053572	0.0385	0.04226	0.0452	0.0025334

Device Test: 35.5 _EnableDelay|EnRisingToSwRising/EN1/3/3///90.9/634//0///@T_ENABLE_DELAY





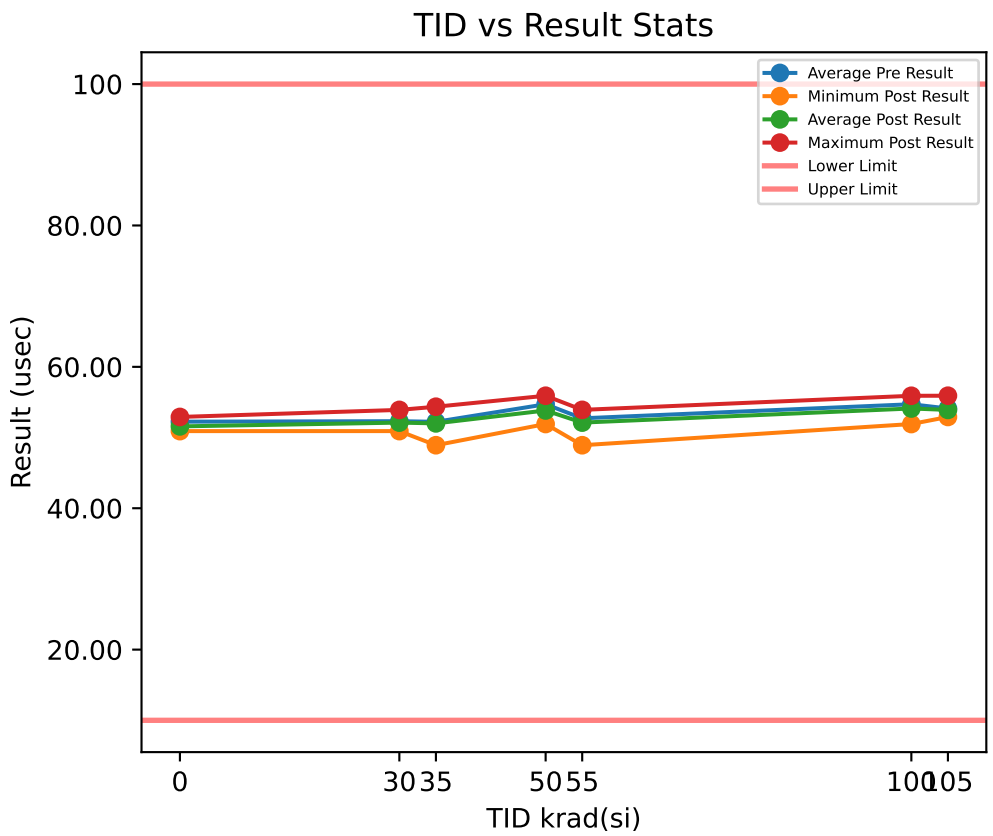
Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

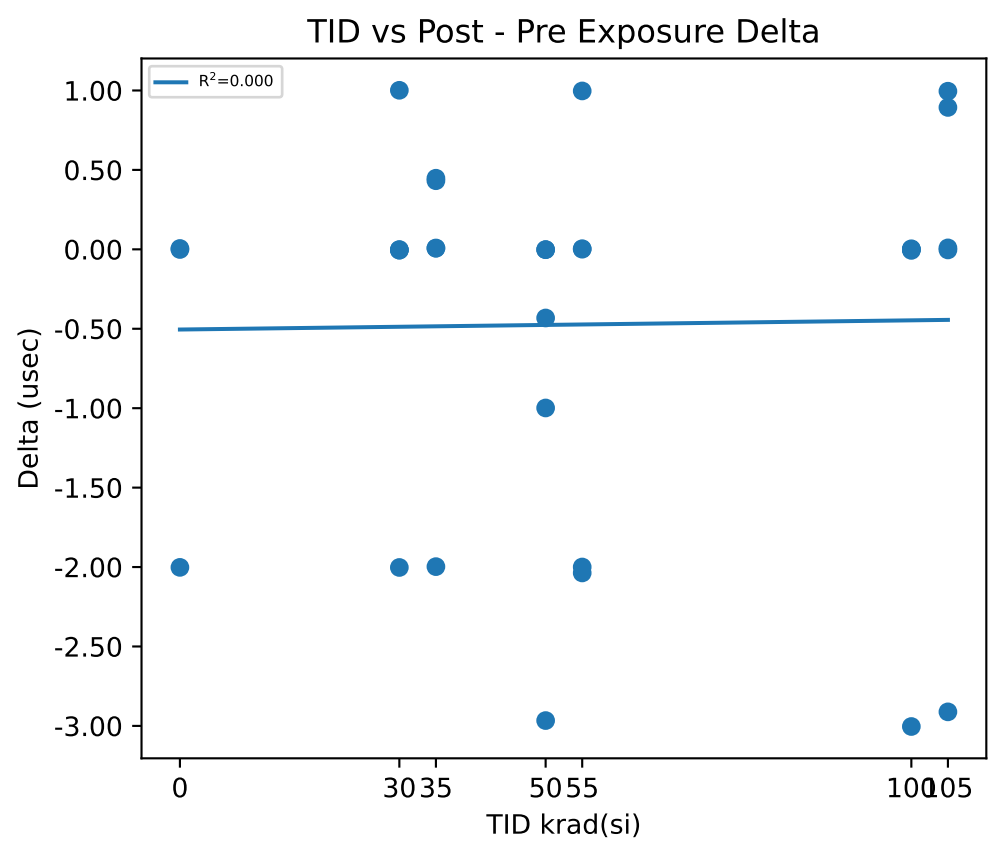
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	49.779	49.862	0.083
2	0	CU2	51.783	51.866	0.0837
3	0	CU3	54.782	55.854	1.072
11	30	Unbiased-30krad	52.785	51.866	-0.9185
12	30	Unbiased-30krad	52.784	49.964	-2.82
13	30	Unbiased-30krad	47.788	47.869	0.0815
14	30	Unbiased-30krad	52.678	49.867	-2.8103
15	30	Unbiased-30krad	51.784	51.866	0.0813
16	35	Biased-30krad	52.786	52.872	0.0852
17	35	Biased-30krad	50.178	50.869	0.691
18	35	Biased-30krad	52.785	49.869	-2.9157
19	35	Biased-30krad	50.788	50.872	0.0846
20	35	Biased-30krad	50.173	50.873	0.7002
30	50	Unbiased-50krad	51.788	51.87	0.0819
31	50	Unbiased-50krad	53.788	51.871	-1.9172
32	50	Unbiased-50krad	52.788	52.869	0.0811
33	50	Unbiased-50krad	54.789	54.87	0.0809
34	50	Unbiased-50krad	49.784	49.868	0.0839
40	55	Biased-50krad	50.786	50.871	0.0856
41	55	Biased-50krad	53.785	52.872	-0.9129
42	55	Biased-50krad	49.785	47.87	-1.9145
43	55	Biased-50krad	53.787	50.869	-2.918
44	55	Biased-50krad	55.787	55.871	0.0835
45	100	Unbiased-100krad	52.789	52.876	0.0869
46	100	Unbiased-100krad	56.788	56.867	0.0787
47	100	Unbiased-100krad	53.025	52.868	-0.1564
48	100	Unbiased-100krad	50.789	48.072	-2.7175
49	100	Unbiased-100krad	51.787	51.766	-0.0207
50	105	Biased-100krad	49.79	47.869	-1.9214
51	105	Biased-100krad	54.789	52.871	-1.9175
52	105	Biased-100krad	54.788	54.869	0.0807
53	105	Biased-100krad	54.793	52.991	-1.8013
54	105	Biased-100krad	52.686	50.869	-1.8166

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.779	52.115	54.782	2.5184	49.862	52.527	55.854	3.0506	0.083	0.4129	1.072	0.5708
30	47.788	51.564	52.785	2.1521	47.869	50.286	51.866	1.6667	-2.82	-1.2772	0.0815	1.4621
35	50.173	51.342	52.786	1.3415	49.869	51.071	52.872	1.0961	-2.9157	-0.27094	0.7002	1.5097
50	49.784	52.588	54.789	1.9254	49.868	52.27	54.87	1.8173	-1.9172	-0.31788	0.0839	0.89405
55	49.785	52.786	55.787	2.4502	47.87	51.671	55.871	2.9498	-2.918	-1.1153	0.0856	1.3047
100	50.789	53.035	56.788	2.2774	48.072	52.49	56.867	3.1422	-2.7175	-0.5458	0.0869	1.218
105	49.79	53.369	54.793	2.1985	47.869	51.894	54.869	2.6582	-1.9214	-1.4752	0.0807	0.87156

Device Test: 35.6 _EnableDelay|EnRisingToSwRising/EN2/3/3///90.9/634//0///@T_ENABLE_DELAY





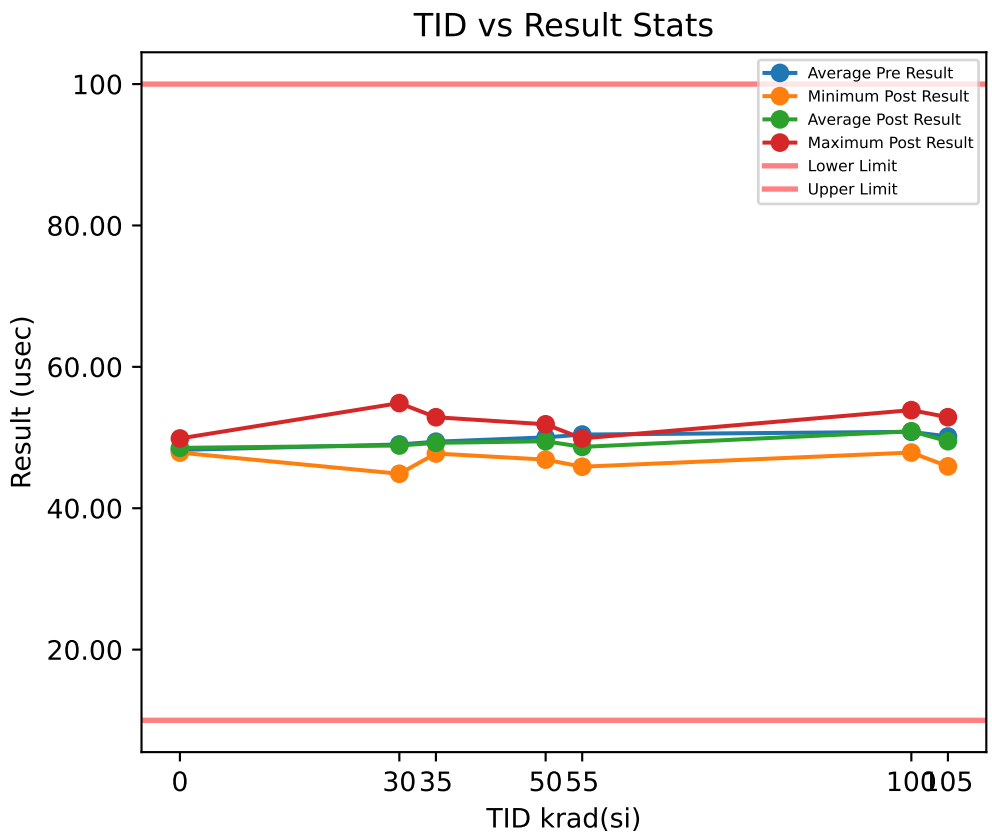
Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

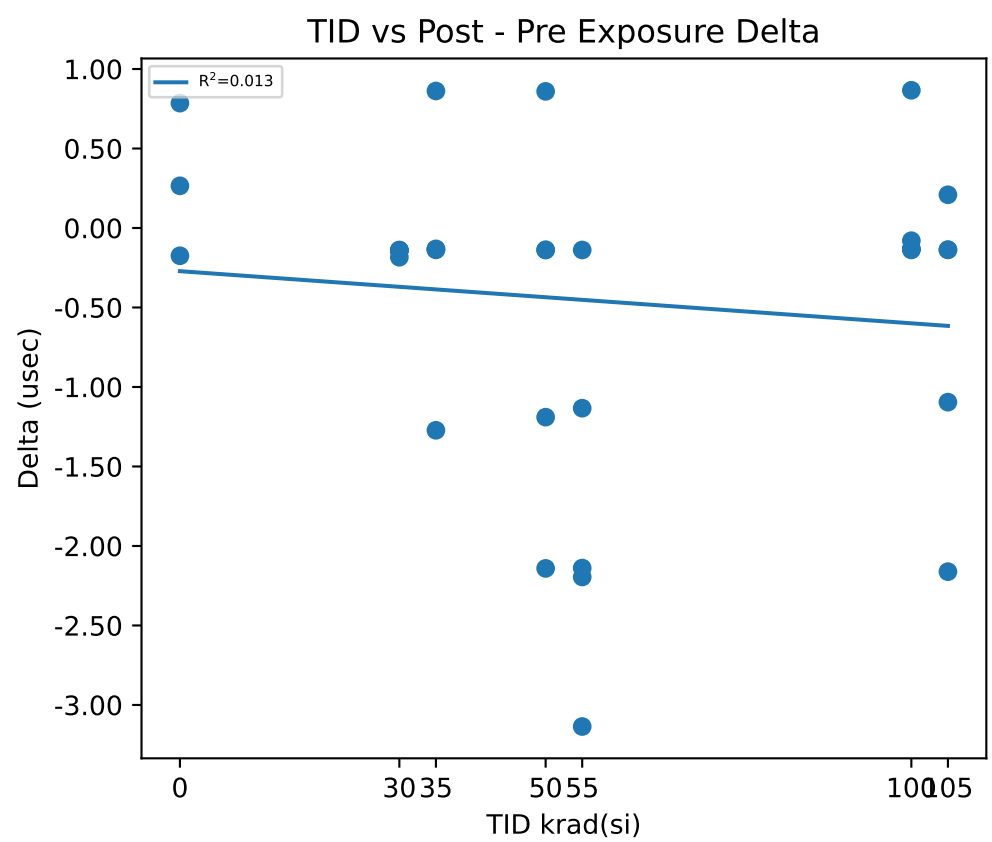
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	50.91	50.909	-0.001
2	0	CU2	52.908	52.913	0.0055
3	0	CU3	52.916	50.914	-2.002
11	30	Unbiased-30krad	50.912	51.914	1.0012
12	30	Unbiased-30krad	50.912	50.911	-0.0011
13	30	Unbiased-30krad	50.919	50.915	-0.0046
14	30	Unbiased-30krad	53.916	53.91	-0.0053
15	30	Unbiased-30krad	54.912	52.909	-2.0026
16	35	Biased-30krad	50.908	50.914	0.0066
17	35	Biased-30krad	50.911	48.913	-1.9974
18	35	Biased-30krad	53.482	53.914	0.4319
19	35	Biased-30krad	51.907	51.916	0.0084
20	35	Biased-30krad	53.911	54.358	0.4477
30	50	Unbiased-50krad	55.915	55.913	-0.0023
31	50	Unbiased-50krad	51.916	51.915	-0.0015
32	50	Unbiased-50krad	55.914	52.948	-2.9664
33	50	Unbiased-50krad	55.895	55.463	-0.4321
34	50	Unbiased-50krad	53.911	52.913	-0.9986
40	55	Biased-50krad	50.917	51.914	0.9971
41	55	Biased-50krad	51.913	51.917	0.0039
42	55	Biased-50krad	50.912	48.912	-1.9997
43	55	Biased-50krad	53.91	53.911	0.0009
44	55	Biased-50krad	55.952	53.914	-2.0371
45	100	Unbiased-100krad	53.917	53.91	-0.0067
46	100	Unbiased-100krad	57.913	54.91	-3.0038
47	100	Unbiased-100krad	53.911	53.911	0.0004
48	100	Unbiased-100krad	51.913	51.911	-0.0014
49	100	Unbiased-100krad	55.904	55.907	0.0035
50	105	Biased-100krad	52.916	53.911	0.9954
51	105	Biased-100krad	55.905	52.993	-2.9116
52	105	Biased-100krad	52.903	52.912	0.0091
53	105	Biased-100krad	55.919	55.915	-0.0038
54	105	Biased-100krad	52.918	53.811	0.8933

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.91	52.245	52.916	1.1556	50.909	51.579	52.913	1.1556	-2.002	-0.66583	0.0055	1.1572
30	50.912	52.314	54.912	1.9487	50.911	52.112	53.91	1.3025	-2.0026	-0.20248	1.0012	1.0963
35	50.908	52.224	53.911	1.4129	48.913	52.003	54.358	2.2326	-1.9974	-0.22056	0.4477	1.0165
50	51.916	54.71	55.915	1.7853	51.915	53.83	55.913	1.753	-2.9664	-0.88018	-0.0015	1.2359
55	50.912	52.721	55.952	2.1812	48.912	52.114	53.914	2.0494	-2.0371	-0.60698	0.9971	1.351
100	51.913	54.711	57.913	2.2793	51.911	54.11	55.907	1.482	-3.0038	-0.6016	0.0035	1.3429
105	52.903	54.112	55.919	1.6431	52.912	53.909	55.915	1.211	-2.9116	-0.20352	0.9954	1.5858

Device Test: 35.7 _EnableDelay|EnRisingToSwRising/EN3/3/3///90.9/634//0///@T_ENABLE_DELAY





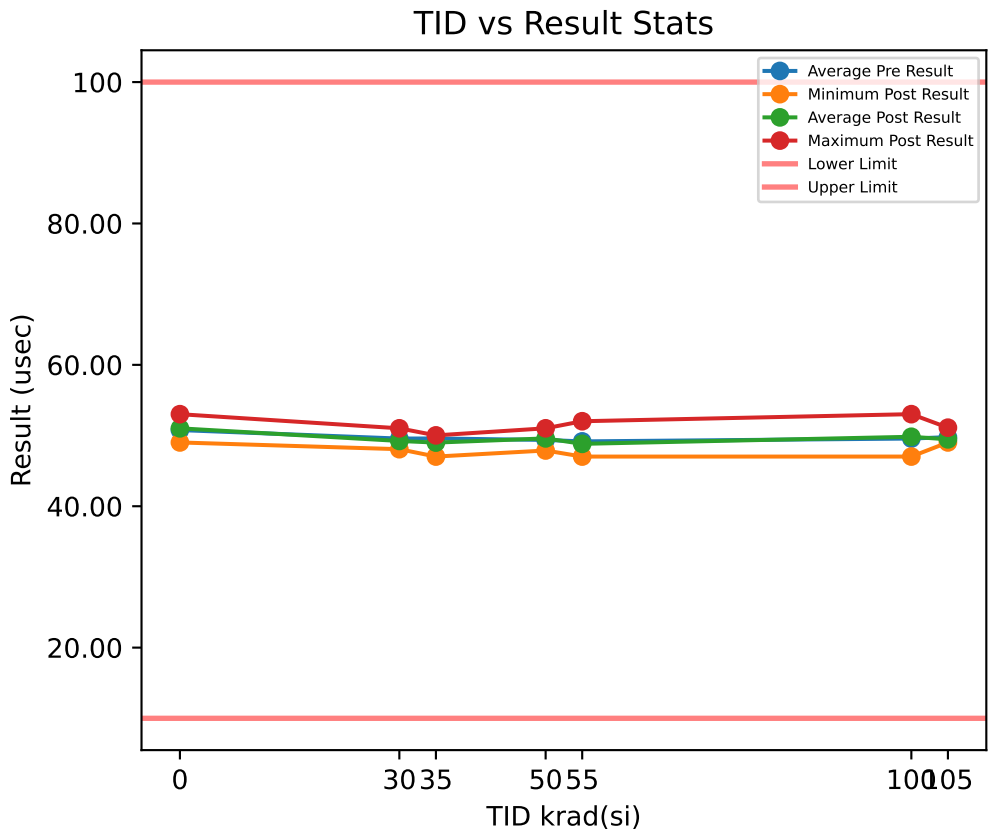
Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

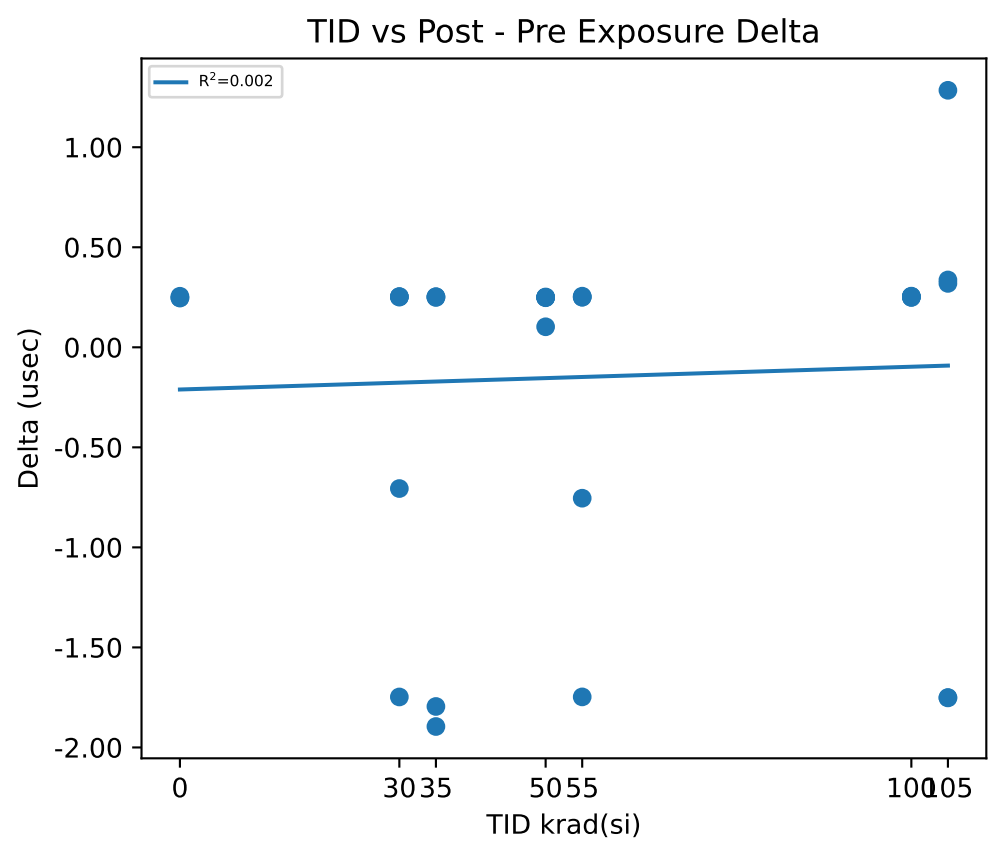
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	48.063	47.888	-0.1746
2	0	CU2	47.604	47.869	0.2653
3	0	CU3	49.084	49.869	0.7853
11	30	Unbiased-30krad	48.014	47.87	-0.1431
12	30	Unbiased-30krad	48.054	47.87	-0.1838
13	30	Unbiased-30krad	45.017	44.876	-0.1415
14	30	Unbiased-30krad	55.013	54.874	-0.1386
15	30	Unbiased-30krad	49.011	48.871	-0.1396
16	35	Biased-30krad	50.009	49.875	-0.1336
17	35	Biased-30krad	48.012	47.874	-0.1376
18	35	Biased-30krad	49.011	47.739	-1.2724
19	35	Biased-30krad	48.008	47.876	-0.1315
20	35	Biased-30krad	52.011	52.872	0.8618
30	50	Unbiased-50krad	51.014	51.874	0.8594
31	50	Unbiased-50krad	51.011	50.873	-0.1377
32	50	Unbiased-50krad	49.014	48.877	-0.1379
33	50	Unbiased-50krad	49.015	46.874	-2.141
34	50	Unbiased-50krad	50.065	48.876	-1.1897
40	55	Biased-50krad	50.015	47.876	-2.1389
41	55	Biased-50krad	51.011	49.877	-1.1335
42	55	Biased-50krad	48.068	45.873	-2.1949
43	55	Biased-50krad	53.009	49.873	-3.1355
44	55	Biased-50krad	50.011	49.873	-0.1382
45	100	Unbiased-100krad	53.015	52.877	-0.1379
46	100	Unbiased-100krad	53.013	53.879	0.8662
47	100	Unbiased-100krad	50.01	49.876	-0.1336
48	100	Unbiased-100krad	48.007	47.878	-0.1295
49	100	Unbiased-100krad	50.006	49.926	-0.0798
50	105	Biased-100krad	47.015	45.92	-1.0953
51	105	Biased-100krad	52.036	49.875	-2.1615
52	105	Biased-100krad	49.014	48.877	-0.1364
53	105	Biased-100krad	52.667	52.876	0.209
54	105	Biased-100krad	50.012	49.874	-0.1374

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.604	48.25	49.084	0.75758	47.869	48.542	49.869	1.1492	-0.1746	0.292	0.7853	0.48051
30	45.017	49.022	55.013	3.6701	44.876	48.872	54.874	3.6742	-0.1838	-0.14932	-0.1386	0.019353
35	48.008	49.41	52.011	1.6734	47.739	49.247	52.872	2.2122	-1.2724	-0.16266	0.8618	0.75556
50	49.014	50.024	51.014	0.99929	46.874	49.475	51.874	1.9489	-2.141	-0.54938	0.8594	1.1475
55	48.068	50.423	53.009	1.7968	45.873	48.675	49.877	1.7892	-3.1355	-1.7482	-0.1382	1.1453
100	48.007	50.81	53.015	2.1712	47.878	50.887	53.879	2.4451	-0.1379	0.07708	0.8662	0.44176
105	47.015	50.149	52.667	2.2931	45.92	49.484	52.876	2.4942	-2.1615	-0.66432	0.209	0.96777

Device Test: 35.8 _EnableDelay|EnRisingToSwRising/EN4/3/3///90.9/634//0///@T_ENABLE_DELAY





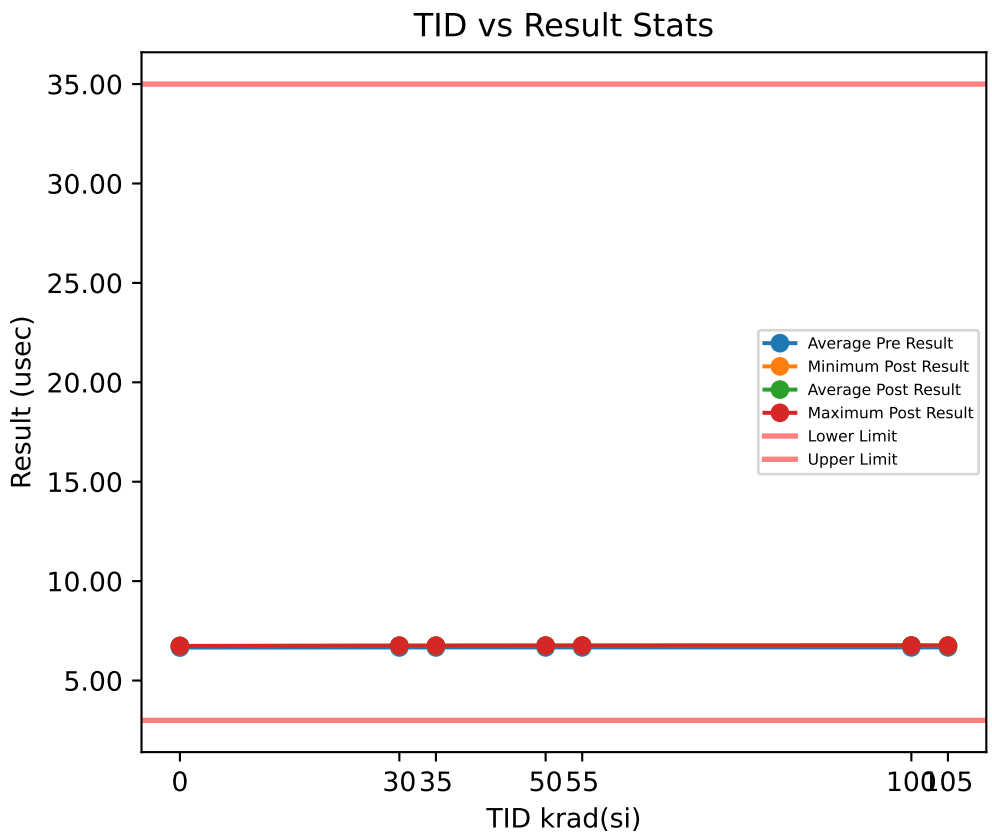
Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

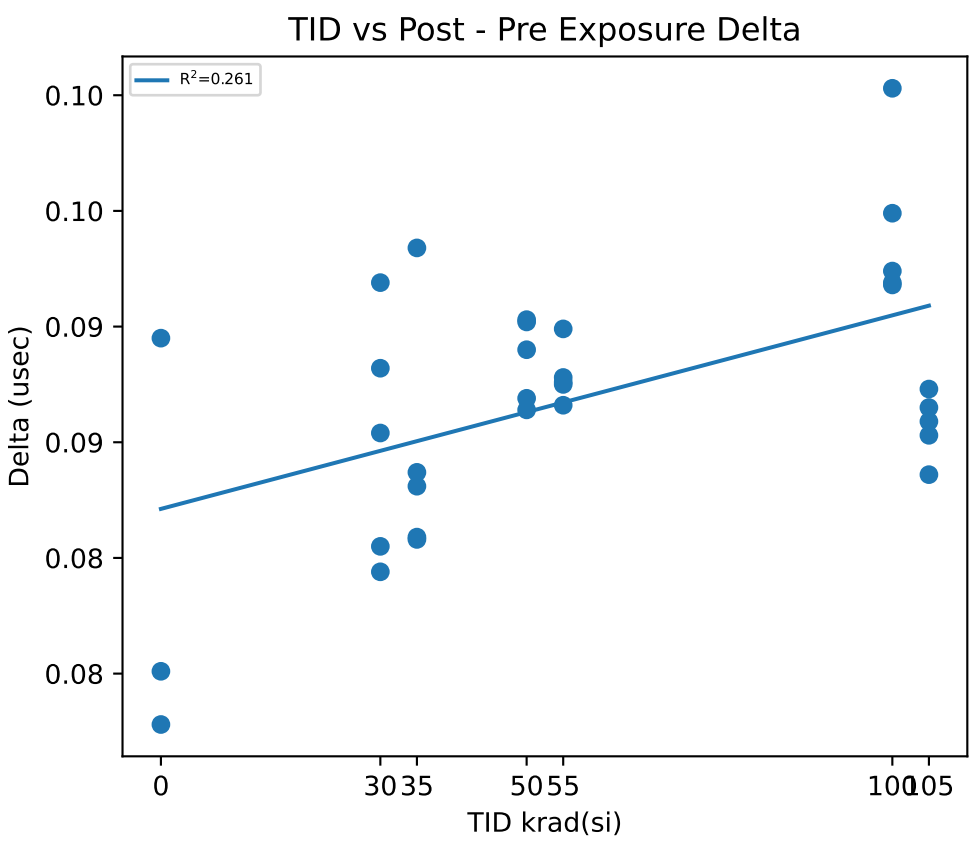
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	48.768	49.023	0.2552
2	0	CU2	52.774	53.021	0.2474
3	0	CU3	50.776	51.022	0.2463
11	30	Unbiased-30krad	48.775	48.069	-0.7059
12	30	Unbiased-30krad	48.771	49.022	0.251
13	30	Unbiased-30krad	48.775	49.027	0.2523
14	30	Unbiased-30krad	48.771	49.025	0.2537
15	30	Unbiased-30krad	52.772	51.024	-1.7476
16	35	Biased-30krad	48.772	49.025	0.2528
17	35	Biased-30krad	51.812	49.916	-1.8953
18	35	Biased-30krad	48.774	49.023	0.249
19	35	Biased-30krad	46.773	47.025	0.2524
20	35	Biased-30krad	51.818	50.023	-1.7952
30	50	Unbiased-50krad	50.776	51.023	0.2477
31	50	Unbiased-50krad	47.782	47.885	0.1026
32	50	Unbiased-50krad	48.776	49.026	0.2498
33	50	Unbiased-50krad	50.774	51.024	0.2496
34	50	Unbiased-50krad	48.773	49.025	0.2515
40	55	Biased-50krad	48.774	47.026	-1.7473
41	55	Biased-50krad	46.77	47.026	0.2556
42	55	Biased-50krad	48.775	49.025	0.2503
43	55	Biased-50krad	49.78	49.026	-0.7542
44	55	Biased-50krad	51.772	52.023	0.2512
45	100	Unbiased-100krad	48.776	49.026	0.2506
46	100	Unbiased-100krad	52.776	53.026	0.2491
47	100	Unbiased-100krad	48.773	49.026	0.2533
48	100	Unbiased-100krad	46.773	47.027	0.2538
49	100	Unbiased-100krad	50.772	51.028	0.2557
50	105	Biased-100krad	50.776	49.024	-1.7523
51	105	Biased-100krad	50.775	51.112	0.3366
52	105	Biased-100krad	47.778	49.062	1.2846
53	105	Biased-100krad	48.777	49.096	0.3194
54	105	Biased-100krad	50.774	49.024	-1.7504

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.768	50.773	52.774	2.0031	49.023	51.022	53.021	1.9992	0.2463	0.24963	0.2552	0.0048521
30	48.771	49.572	52.772	1.7884	48.069	49.233	51.024	1.0833	-1.7476	-0.3393	0.2537	0.88992
35	46.773	49.59	51.818	2.1894	47.025	49.002	50.023	1.2029	-1.8953	-0.58726	0.2528	1.1489
50	47.782	49.376	50.776	1.3397	47.885	49.597	51.024	1.3836	0.1026	0.22024	0.2515	0.065777
55	46.77	49.174	51.772	1.8176	47.026	48.825	52.023	2.0482	-1.7473	-0.34888	0.2556	0.89504
100	46.773	49.574	52.776	2.2812	47.027	49.827	53.026	2.2801	0.2491	0.2525	0.2557	0.0026334
105	47.778	49.776	50.776	1.413	49.024	49.464	51.112	0.92179	-1.7523	-0.31242	1.2846	1.3704

Device Test: 35.9 _EnableDelay|EnFallingToSwFalling/EN1/3/3///90.9/634//0///@T_DISABLE_DELAY





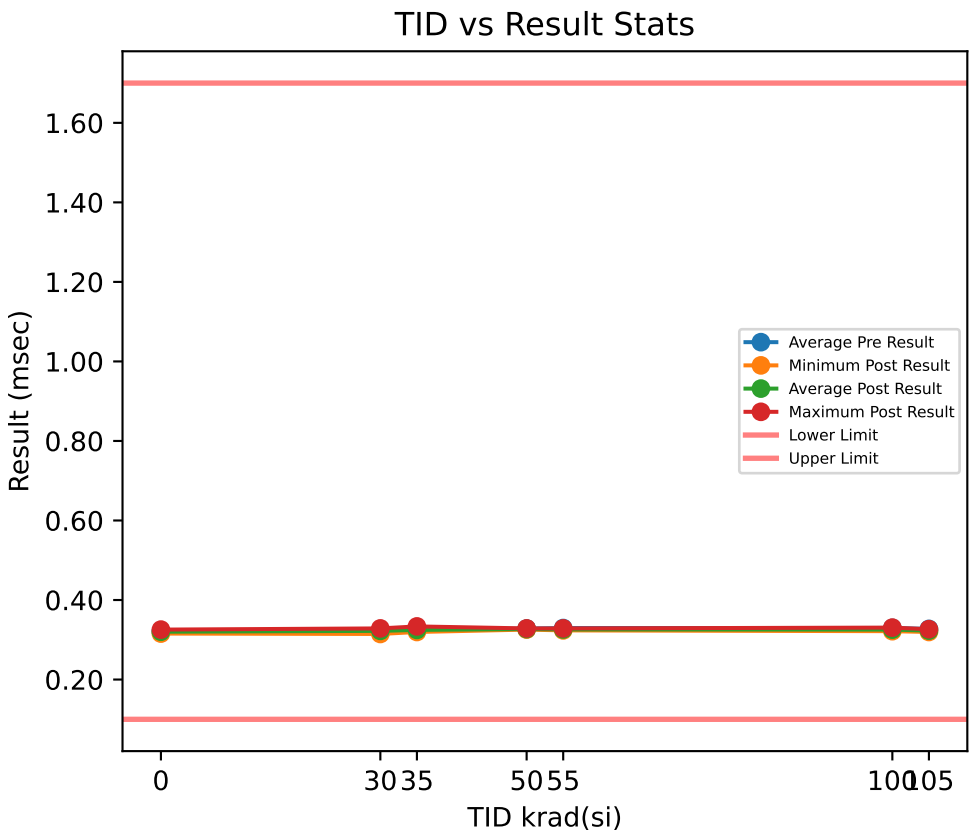
Test Results (Lower Limit = 3.0, Upper Limit = 35.0 (usec))

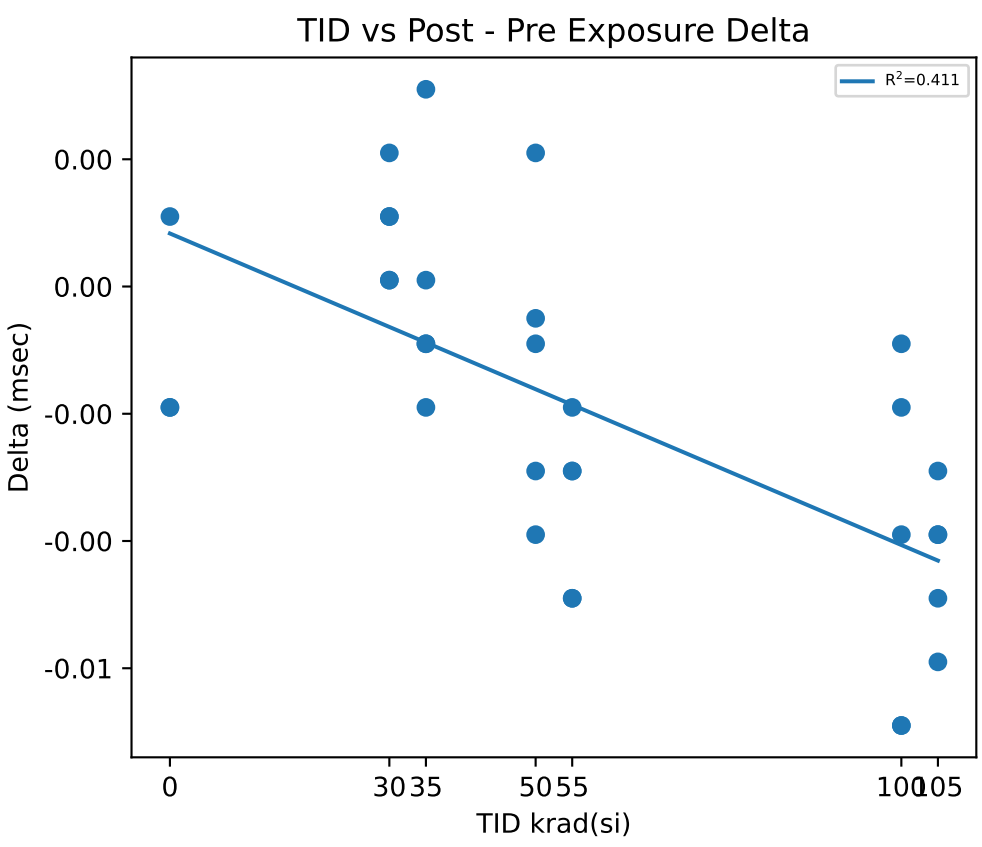
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.6624	6.7375	0.0751
2	0	CU2	6.6485	6.738	0.0895
3	0	CU3	6.6675	6.7403	0.0728
11	30	Unbiased-30krad	6.6656	6.7461	0.0805
12	30	Unbiased-30krad	6.657	6.7489	0.0919
13	30	Unbiased-30krad	6.6672	6.7466	0.0794
14	30	Unbiased-30krad	6.6647	6.7501	0.0854
15	30	Unbiased-30krad	6.6642	6.7524	0.0882
16	35	Biased-30krad	6.6557	6.7491	0.0934
17	35	Biased-30krad	6.6681	6.7518	0.0837
18	35	Biased-30krad	6.67	6.7509	0.0809
19	35	Biased-30krad	6.6669	6.7477	0.0808
20	35	Biased-30krad	6.6662	6.7493	0.0831
30	50	Unbiased-50krad	6.668	6.757	0.089
31	50	Unbiased-50krad	6.6609	6.7511	0.0902
32	50	Unbiased-50krad	6.6675	6.7544	0.0869
33	50	Unbiased-50krad	6.6689	6.7553	0.0864
34	50	Unbiased-50krad	6.6682	6.7585	0.0903
40	55	Biased-50krad	6.666	6.7536	0.0876
41	55	Biased-50krad	6.6665	6.7564	0.0899
42	55	Biased-50krad	6.6688	6.7554	0.0866
43	55	Biased-50krad	6.6674	6.7552	0.0878
44	55	Biased-50krad	6.6685	6.756	0.0875
45	100	Unbiased-100krad	6.6655	6.7579	0.0924
46	100	Unbiased-100krad	6.666	6.7578	0.0918
47	100	Unbiased-100krad	6.6673	6.7622	0.0949
48	100	Unbiased-100krad	6.6606	6.7609	0.1003
49	100	Unbiased-100krad	6.6703	6.7622	0.0919
50	105	Biased-100krad	6.6699	6.7564	0.0865
51	105	Biased-100krad	6.6667	6.754	0.0873
52	105	Biased-100krad	6.6689	6.7542	0.0853
53	105	Biased-100krad	6.6688	6.7524	0.0836
54	105	Biased-100krad	6.6697	6.7556	0.0859

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6485	6.6595	6.6675	0.0098338	6.7375	6.7386	6.7403	0.0014933	0.0728	0.079133	0.0895	0.0090512
30	6.657	6.6637	6.6672	0.0039367	6.7461	6.7488	6.7524	0.0025879	0.0794	0.08508	0.0919	0.0052342
35	6.6557	6.6654	6.67	0.0055997	6.7477	6.7498	6.7518	0.0016087	0.0808	0.08438	0.0934	0.0052055
50	6.6609	6.6667	6.6689	0.003281	6.7511	6.7553	6.7585	0.0028094	0.0864	0.08856	0.0903	0.0018257
55	6.666	6.6674	6.6688	0.0012178	6.7536	6.7553	6.7564	0.0010733	0.0866	0.08788	0.0899	0.0012194
100	6.6606	6.6659	6.6703	0.0035204	6.7578	6.7602	6.7622	0.0022102	0.0918	0.09426	0.1003	0.0036046
105	6.6667	6.6688	6.6699	0.0012689	6.7524	6.7545	6.7564	0.0015466	0.0836	0.08572	0.0873	0.0013971

Device Test: 36.1 _EnableDelay|EnRisingToSwRising/EN1/7/7///90.9/634//0///@T_ENABLE_DELAY_VIN





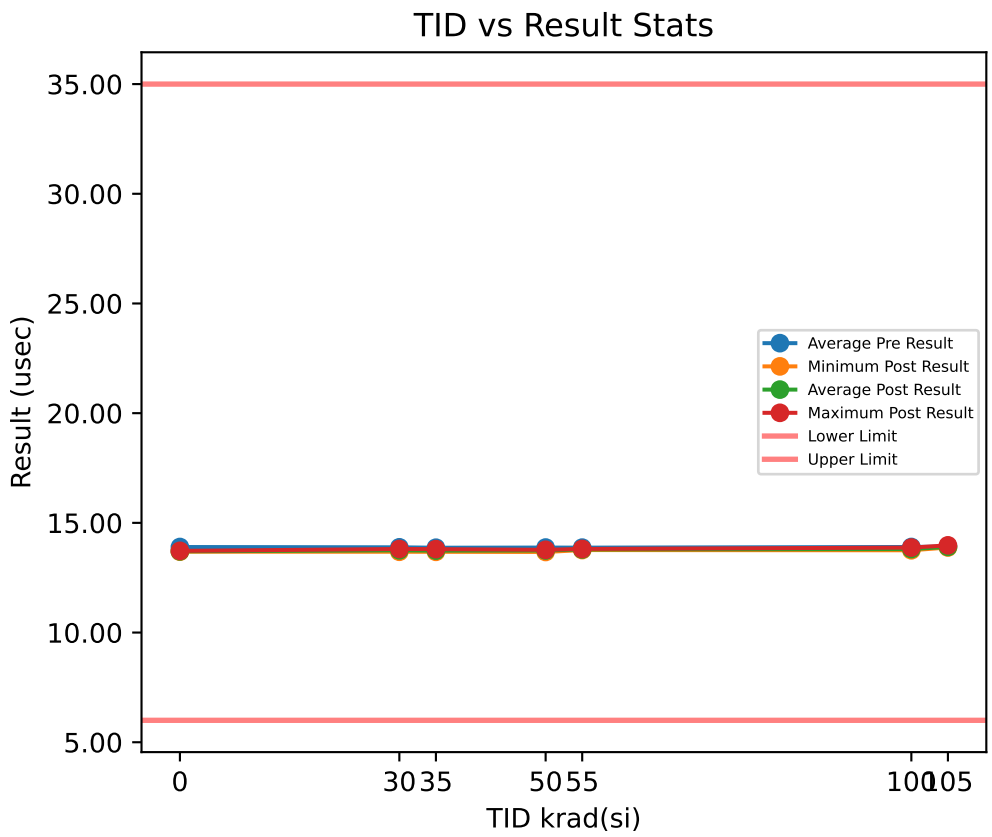
Test Results (Lower Limit = 0.1, Upper Limit = 1.7 (msec))

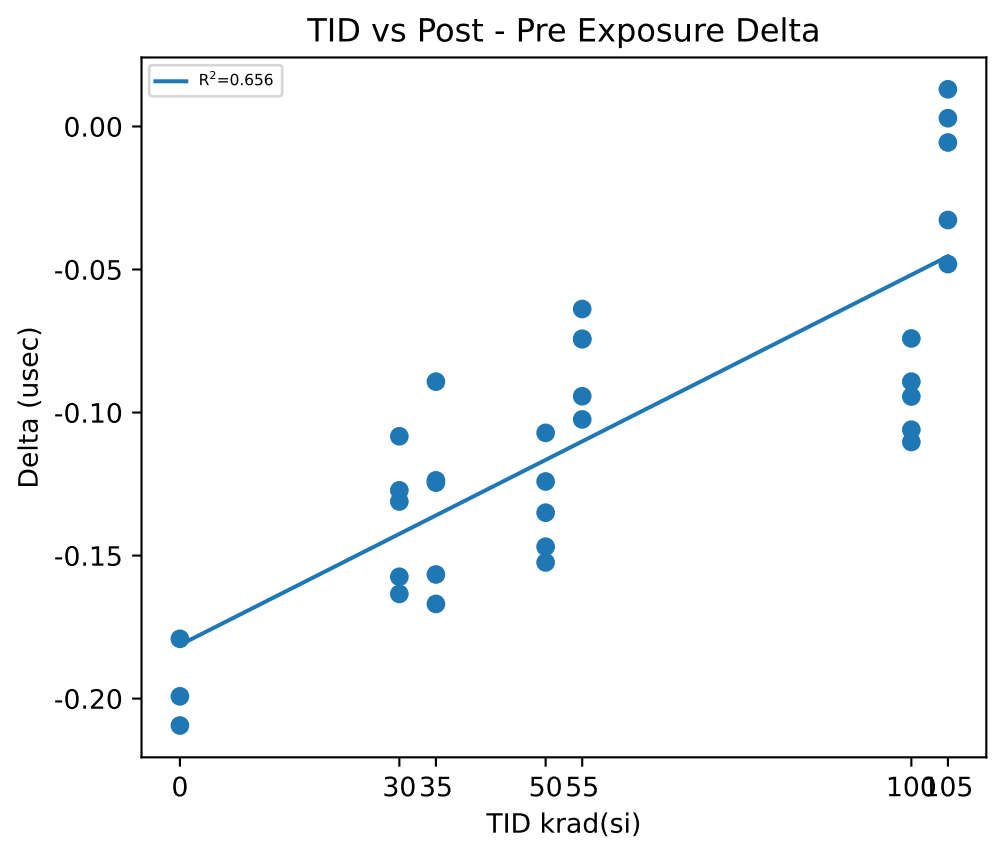
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3175	0.3156	-0.0019
2	0	CU2	0.3245	0.3256	0.0011
3	0	CU3	0.3215	0.3196	-0.0019
11	30	Unbiased-30krad	0.3225	0.3246	0.0021
12	30	Unbiased-30krad	0.3285	0.3286	0.0001
13	30	Unbiased-30krad	0.3215	0.3216	0.0001
14	30	Unbiased-30krad	0.3215	0.3226	0.0011
15	30	Unbiased-30krad	0.3135	0.3146	0.0011
16	35	Biased-30krad	0.3285	0.3276	-0.0009
17	35	Biased-30krad	0.3215	0.3196	-0.0019
18	35	Biased-30krad	0.3215	0.3206	-0.0009
19	35	Biased-30krad	0.3195	0.3226	0.0031
20	35	Biased-30krad	0.3335	0.3336	0.0001
30	50	Unbiased-50krad	0.3285	0.3256	-0.0029
31	50	Unbiased-50krad	0.3281	0.3276	-0.0005
32	50	Unbiased-50krad	0.3295	0.3256	-0.0039
33	50	Unbiased-50krad	0.3255	0.3276	0.0021
34	50	Unbiased-50krad	0.3295	0.3286	-0.0009
40	55	Biased-50krad	0.3285	0.3236	-0.0049
41	55	Biased-50krad	0.3295	0.3266	-0.0029
42	55	Biased-50krad	0.3275	0.3246	-0.0029
43	55	Biased-50krad	0.3305	0.3286	-0.0019
44	55	Biased-50krad	0.3315	0.3266	-0.0049
45	100	Unbiased-100krad	0.3285	0.3276	-0.0009
46	100	Unbiased-100krad	0.3285	0.3216	-0.0069
47	100	Unbiased-100krad	0.3315	0.3246	-0.0069
48	100	Unbiased-100krad	0.3255	0.3236	-0.0019
49	100	Unbiased-100krad	0.3345	0.3306	-0.0039
50	105	Biased-100krad	0.3255	0.3226	-0.0029
51	105	Biased-100krad	0.3295	0.3236	-0.0059
52	105	Biased-100krad	0.3305	0.3266	-0.0039
53	105	Biased-100krad	0.3235	0.3196	-0.0039
54	105	Biased-100krad	0.3275	0.3226	-0.0049

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3175	0.32117	0.3245	0.0035119	0.3156	0.32027	0.3256	0.0050332	-0.0019	-0.0009	0.0011	0.0017321
30	0.3135	0.3215	0.3285	0.0053385	0.3146	0.3224	0.3286	0.0051186	0.0001	0.0009	0.0021	0.00083666
35	0.3195	0.3249	0.3335	0.0058992	0.3196	0.3248	0.3336	0.0058052	-0.0019	-0.0001	0.0031	0.0019235
50	0.3255	0.32822	0.3295	0.0016407	0.3256	0.327	0.3286	0.0013416	-0.0039	-0.00122	0.0021	0.0023264
55	0.3275	0.3295	0.3315	0.0015811	0.3236	0.326	0.3286	0.0019494	-0.0049	-0.0035	-0.0019	0.0013416
100	0.3255	0.3297	0.3345	0.0034205	0.3216	0.3256	0.3306	0.0035355	-0.0069	-0.0041	-0.0009	0.0027749
105	0.3235	0.3273	0.3305	0.0028636	0.3196	0.323	0.3266	0.00251	-0.0059	-0.0043	-0.0029	0.0011402

Device Test: 36.10 _EnableDelay|EnFallingToSwFalling/EN2/7/7///90.9/634//0///@T_DISABLE_DELAY





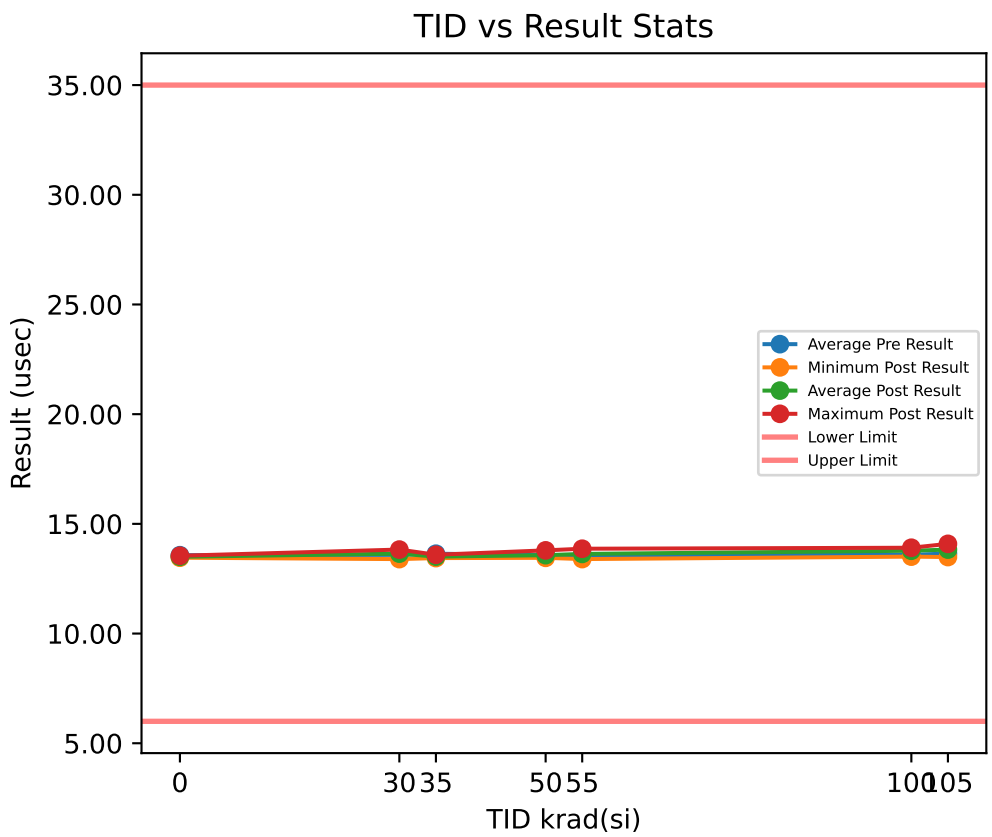
Test Results (Lower Limit = 6.0, Upper Limit = 35.0 (usec))

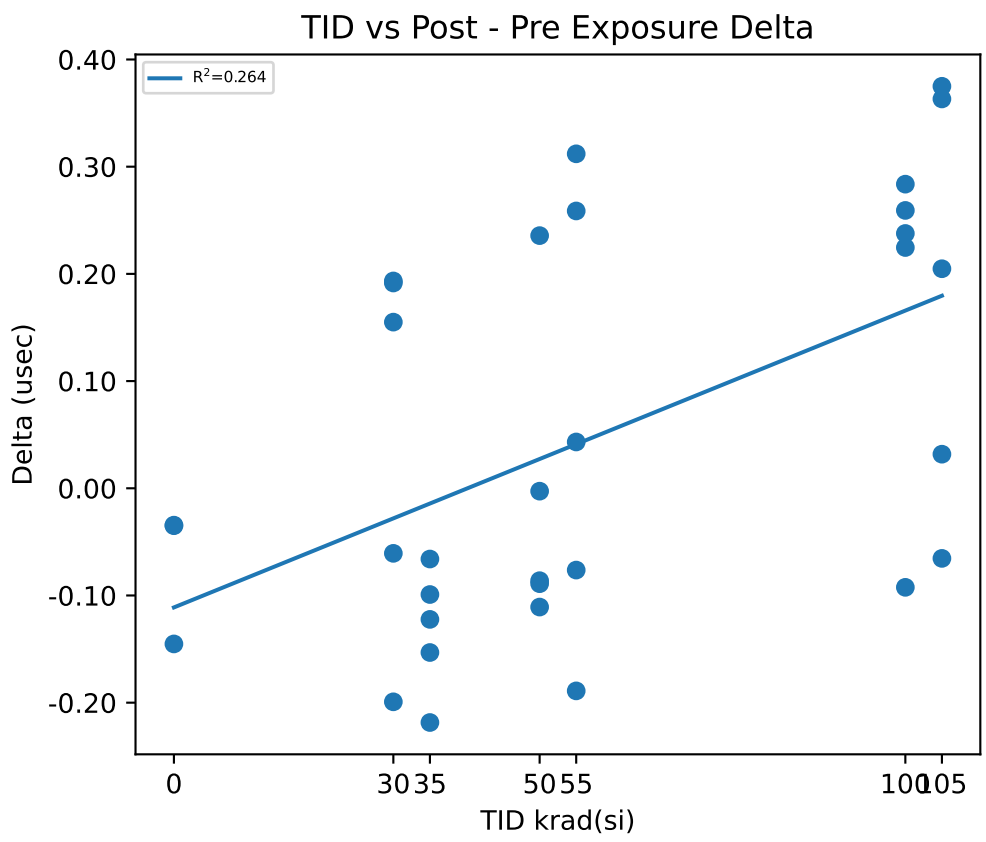
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	13.88	13.701	-0.1791
2	0	CU2	13.895	13.685	-0.2094
3	0	CU3	13.923	13.724	-0.1992
11	30	Unbiased-30krad	13.884	13.726	-0.1574
12	30	Unbiased-30krad	13.846	13.682	-0.1634
13	30	Unbiased-30krad	13.894	13.763	-0.1311
14	30	Unbiased-30krad	13.917	13.809	-0.1083
15	30	Unbiased-30krad	13.886	13.759	-0.1272
16	35	Biased-30krad	13.877	13.71	-0.1669
17	35	Biased-30krad	13.921	13.798	-0.1237
18	35	Biased-30krad	13.772	13.683	-0.0892
19	35	Biased-30krad	13.804	13.68	-0.1245
20	35	Biased-30krad	13.959	13.802	-0.1566
30	50	Unbiased-50krad	13.797	13.673	-0.1241
31	50	Unbiased-50krad	13.89	13.738	-0.1524
32	50	Unbiased-50krad	13.907	13.772	-0.135
33	50	Unbiased-50krad	13.878	13.771	-0.1071
34	50	Unbiased-50krad	13.901	13.754	-0.1469
40	55	Biased-50krad	13.856	13.781	-0.0744
41	55	Biased-50krad	13.875	13.811	-0.0638
42	55	Biased-50krad	13.87	13.796	-0.0742
43	55	Biased-50krad	13.897	13.795	-0.1024
44	55	Biased-50krad	13.855	13.76	-0.0943
45	100	Unbiased-100krad	13.859	13.753	-0.106
46	100	Unbiased-100krad	13.86	13.75	-0.1103
47	100	Unbiased-100krad	13.895	13.806	-0.0892
48	100	Unbiased-100krad	13.947	13.873	-0.0741
49	100	Unbiased-100krad	13.938	13.844	-0.0944
50	105	Biased-100krad	13.891	13.894	0.0029
51	105	Biased-100krad	13.962	13.975	0.013
52	105	Biased-100krad	13.929	13.881	-0.0481
53	105	Biased-100krad	13.883	13.877	-0.0056
54	105	Biased-100krad	13.929	13.896	-0.0327

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.88	13.899	13.923	0.022008	13.685	13.703	13.724	0.019477	-0.2094	-0.1959	-0.1791	0.015417
30	13.846	13.885	13.917	0.025715	13.682	13.748	13.809	0.046882	-0.1634	-0.13748	-0.1083	0.022729
35	13.772	13.867	13.959	0.078122	13.68	13.735	13.802	0.060836	-0.1669	-0.13218	-0.0892	0.030741
50	13.797	13.874	13.907	0.044659	13.673	13.741	13.772	0.040761	-0.1524	-0.1331	-0.1071	0.01819
55	13.855	13.871	13.897	0.017369	13.76	13.789	13.811	0.019042	-0.1024	-0.08182	-0.0638	0.015946
100	13.859	13.9	13.947	0.041564	13.75	13.805	13.873	0.054278	-0.1103	-0.0948	-0.0741	0.014367
105	13.883	13.919	13.962	0.031997	13.877	13.905	13.975	0.040121	-0.0481	-0.0141	0.013	0.025483

Device Test: 36.11 _EnableDelay|EnFallingToSwFalling/EN3/7/7///90.9/634//0///@T_DISABLE_DELAY





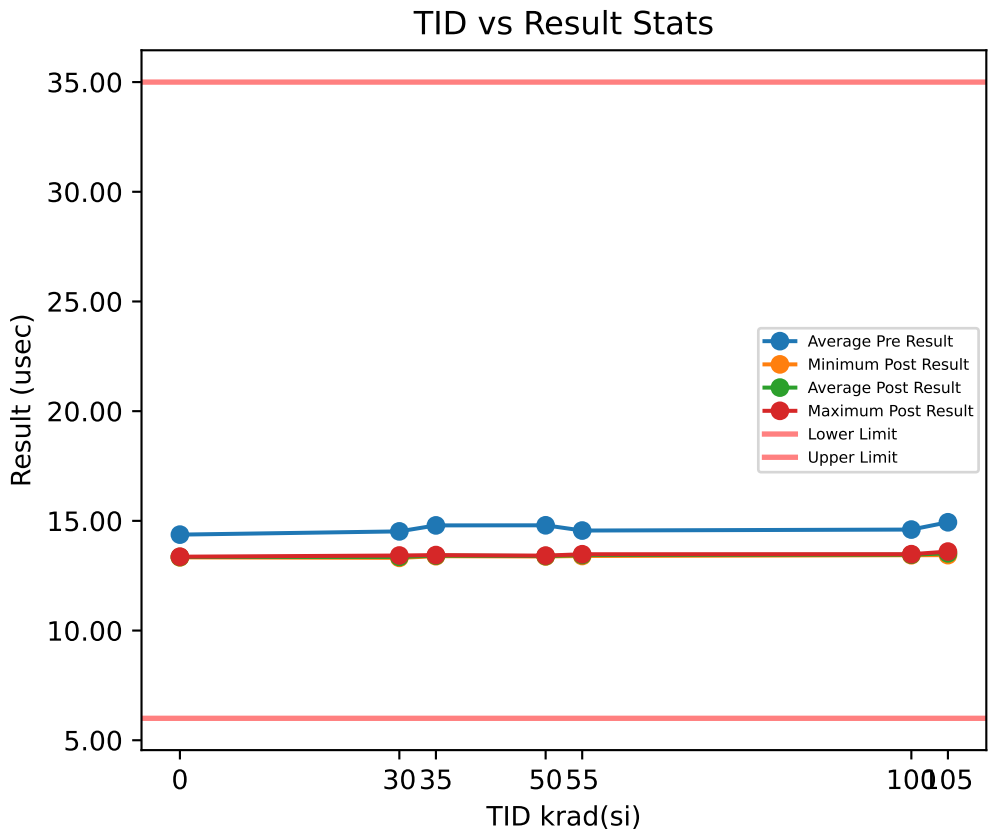
Test Results (Lower Limit = 6.0, Upper Limit = 35.0 (usec))

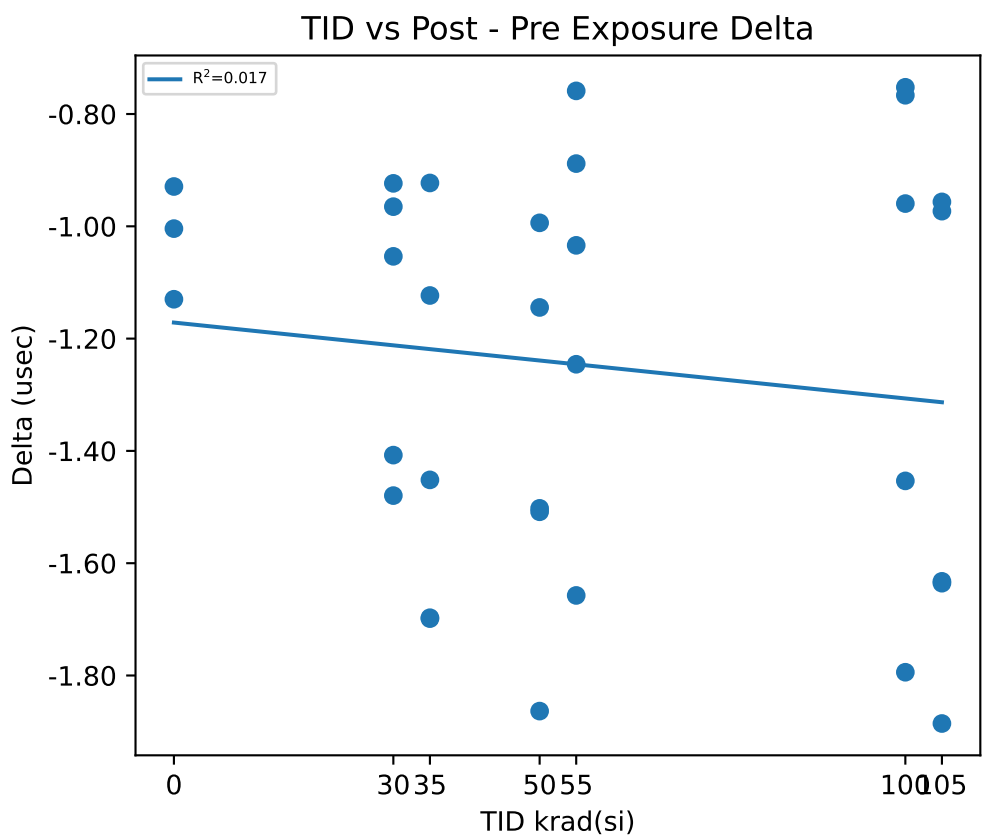
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	13.581	13.546	-0.0344
2	0	CU2	13.602	13.457	-0.1452
3	0	CU3	13.532	13.497	-0.0349
11	30	Unbiased-30krad	13.592	13.393	-0.1992
12	30	Unbiased-30krad	13.637	13.828	0.1915
13	30	Unbiased-30krad	13.576	13.515	-0.0607
14	30	Unbiased-30krad	13.581	13.774	0.1934
15	30	Unbiased-30krad	13.55	13.705	0.155
16	35	Biased-30krad	13.619	13.466	-0.1532
17	35	Biased-30krad	13.568	13.502	-0.066
18	35	Biased-30krad	13.658	13.44	-0.2185
19	35	Biased-30krad	13.713	13.59	-0.1223
20	35	Biased-30krad	13.636	13.537	-0.0991
30	50	Unbiased-50krad	13.663	13.66	-0.0027
31	50	Unbiased-50krad	13.59	13.504	-0.0862
32	50	Unbiased-50krad	13.562	13.451	-0.1108
33	50	Unbiased-50krad	13.556	13.792	0.2357
34	50	Unbiased-50krad	13.546	13.457	-0.089
40	55	Biased-50krad	13.565	13.824	0.2587
41	55	Biased-50krad	13.554	13.866	0.312
42	55	Biased-50krad	13.584	13.395	-0.189
43	55	Biased-50krad	13.54	13.464	-0.0763
44	55	Biased-50krad	13.559	13.602	0.0432
45	100	Unbiased-100krad	13.599	13.858	0.2592
46	100	Unbiased-100krad	13.628	13.912	0.2837
47	100	Unbiased-100krad	13.599	13.506	-0.0924
48	100	Unbiased-100krad	13.55	13.787	0.2377
49	100	Unbiased-100krad	13.584	13.809	0.2246
50	105	Biased-100krad	13.552	13.487	-0.0654
51	105	Biased-100krad	13.713	14.088	0.375
52	105	Biased-100krad	13.695	14.058	0.3632
53	105	Biased-100krad	13.64	13.845	0.2048
54	105	Biased-100krad	13.625	13.657	0.0318

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.532	13.572	13.602	0.036146	13.457	13.5	13.546	0.044789	-0.1452	-0.0715	-0.0344	0.063827
30	13.55	13.587	13.637	0.031759	13.393	13.643	13.828	0.1831	-0.1992	0.056	0.1934	0.17733
35	13.568	13.639	13.713	0.053048	13.44	13.507	13.59	0.059251	-0.2185	-0.13182	-0.066	0.058017
50	13.546	13.583	13.663	0.047308	13.451	13.573	13.792	0.14884	-0.1108	-0.0106	0.2357	0.14373
55	13.54	13.56	13.584	0.016116	13.395	13.63	13.866	0.21047	-0.189	0.06972	0.312	0.21411
100	13.55	13.592	13.628	0.028399	13.506	13.774	13.912	0.15733	-0.0924	0.18256	0.2837	0.15533
105	13.552	13.645	13.713	0.063443	13.487	13.827	14.088	0.25803	-0.0654	0.18188	0.375	0.19645

Device Test: 36.12 _EnableDelay|EnFallingToSwFalling/EN4/7/7///90.9/634//0///@T_DISABLE_DELAY





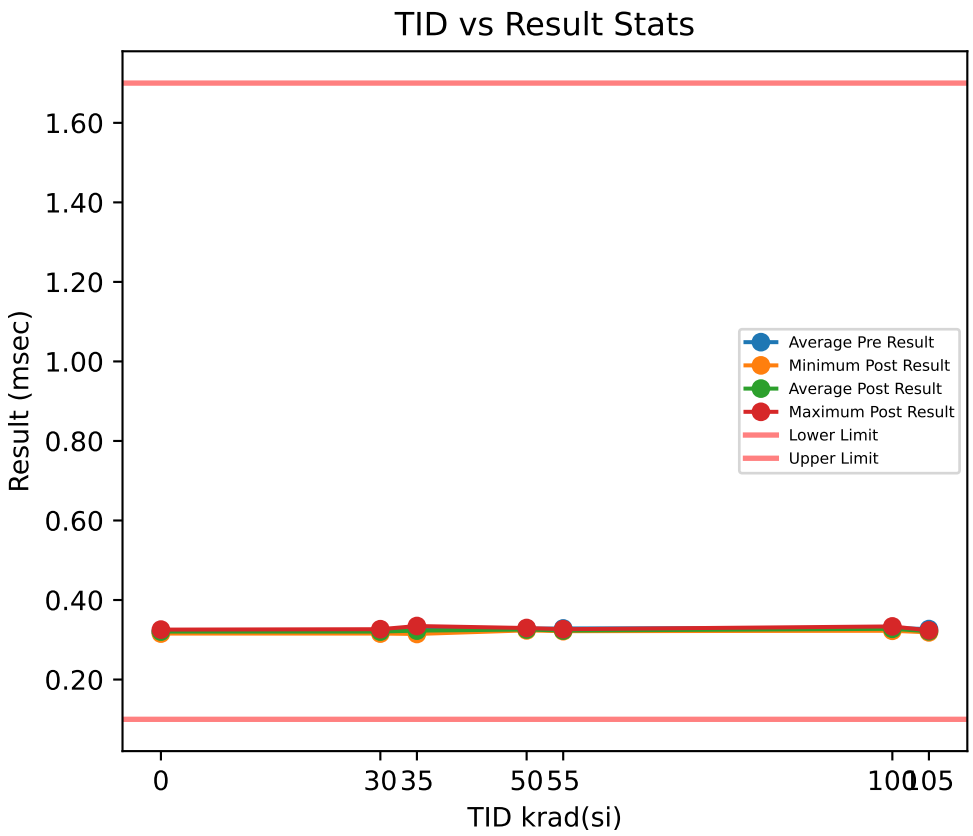
Test Results (Lower Limit = 6.0, Upper Limit = 35.0 (usec))

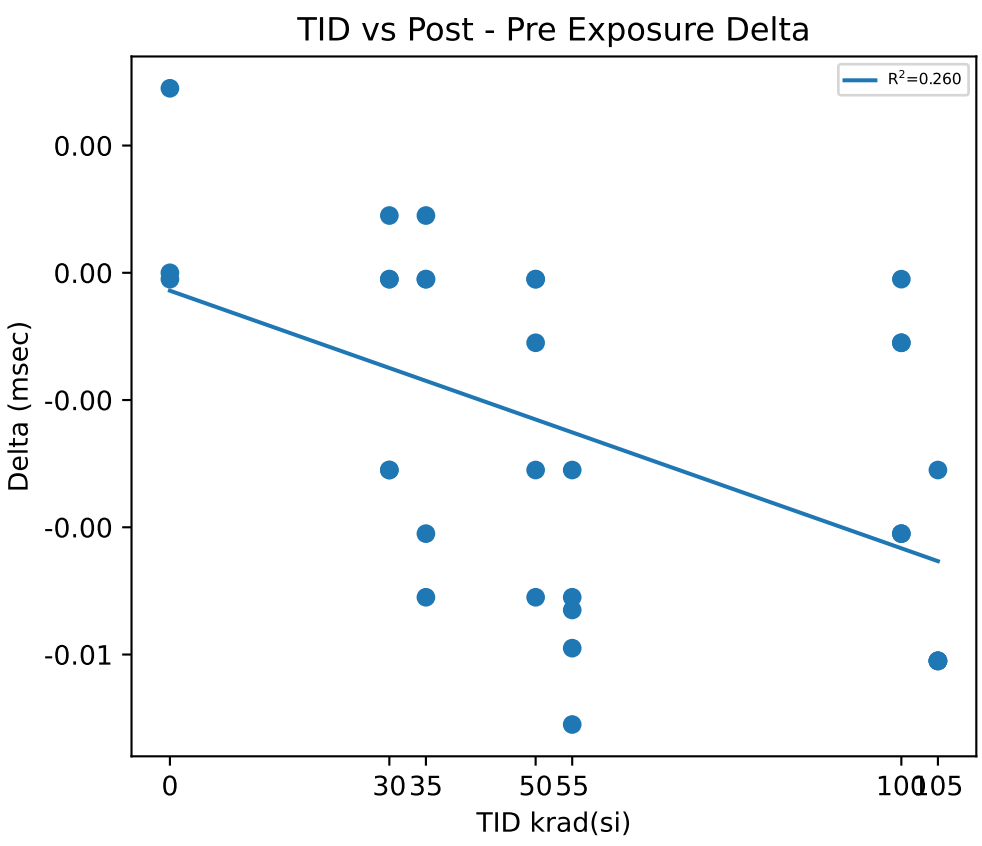
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	14.265	13.336	-0.9291
2	0	CU2	14.482	13.352	-1.1299
3	0	CU3	14.371	13.367	-1.0041
11	30	Unbiased-30krad	14.311	13.346	-0.965
12	30	Unbiased-30krad	14.828	13.421	-1.4075
13	30	Unbiased-30krad	14.839	13.36	-1.4796
14	30	Unbiased-30krad	14.386	13.332	-1.0535
15	30	Unbiased-30krad	14.237	13.313	-0.9235
16	35	Biased-30krad	14.512	13.389	-1.1232
17	35	Biased-30krad	15.116	13.419	-1.6971
18	35	Biased-30krad	14.858	13.406	-1.4516
19	35	Biased-30krad	14.341	13.419	-0.9228
20	35	Biased-30krad	15.139	13.44	-1.6987
30	50	Unbiased-50krad	14.918	13.415	-1.5023
31	50	Unbiased-50krad	14.543	13.398	-1.1445
32	50	Unbiased-50krad	15.252	13.389	-1.8634
33	50	Unbiased-50krad	14.37	13.377	-0.9938
34	50	Unbiased-50krad	14.905	13.396	-1.5084
40	55	Biased-50krad	15.119	13.461	-1.6574
41	55	Biased-50krad	14.237	13.479	-0.7588
42	55	Biased-50krad	14.443	13.409	-1.0339
43	55	Biased-50krad	14.644	13.398	-1.2457
44	55	Biased-50krad	14.35	13.461	-0.8883
45	100	Unbiased-100krad	15.268	13.474	-1.7942
46	100	Unbiased-100krad	14.913	13.46	-1.4534
47	100	Unbiased-100krad	14.2	13.433	-0.7666
48	100	Unbiased-100krad	14.441	13.481	-0.9595
49	100	Unbiased-100krad	14.194	13.441	-0.7524
50	105	Biased-100krad	15.073	13.438	-1.6356
51	105	Biased-100krad	15.232	13.6	-1.6323
52	105	Biased-100krad	14.502	13.529	-0.973
53	105	Biased-100krad	14.505	13.548	-0.9565
54	105	Biased-100krad	15.367	13.481	-1.8855

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.265	14.373	14.482	0.10831	13.336	13.352	13.367	0.015451	-1.1299	-1.021	-0.9291	0.10147
30	14.237	14.52	14.839	0.29121	13.313	13.354	13.421	0.041002	-1.4796	-1.1658	-0.9235	0.2591
35	14.341	14.793	15.139	0.35755	13.389	13.415	13.44	0.018996	-1.6987	-1.3787	-0.9228	0.34721
50	14.37	14.798	15.252	0.34644	13.377	13.395	13.415	0.014095	-1.8634	-1.4025	-0.9938	0.34176
55	14.237	14.559	15.119	0.34684	13.398	13.442	13.479	0.035626	-1.6574	-1.1168	-0.7588	0.35218
100	14.194	14.603	15.268	0.47304	13.433	13.458	13.481	0.020496	-1.7942	-1.1452	-0.7524	0.46052
105	14.502	14.936	15.367	0.40817	13.438	13.519	13.6	0.06221	-1.8855	-1.4166	-0.9565	0.4251

Device Test: 36.2 _EnableDelay|EnRisingToSwRising/EN2/7/7///90.9/634//0///@T_ENABLE_DELAY_VIN





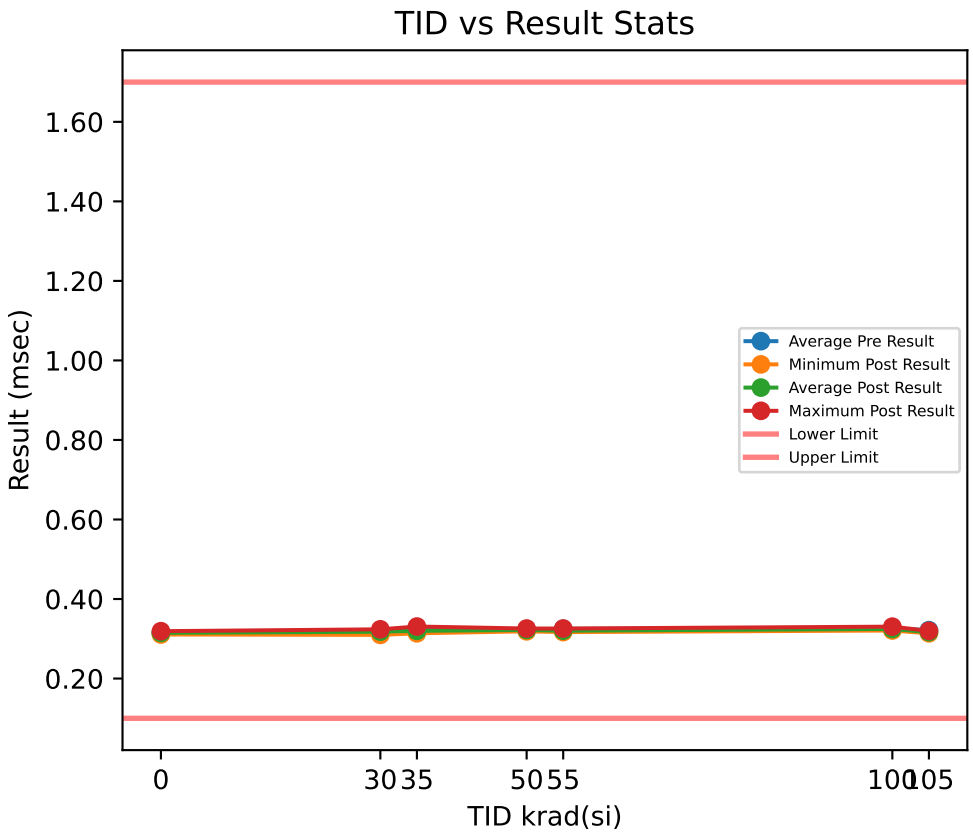
Test Results (Lower Limit = 0.1, Upper Limit = 1.7 (msec))

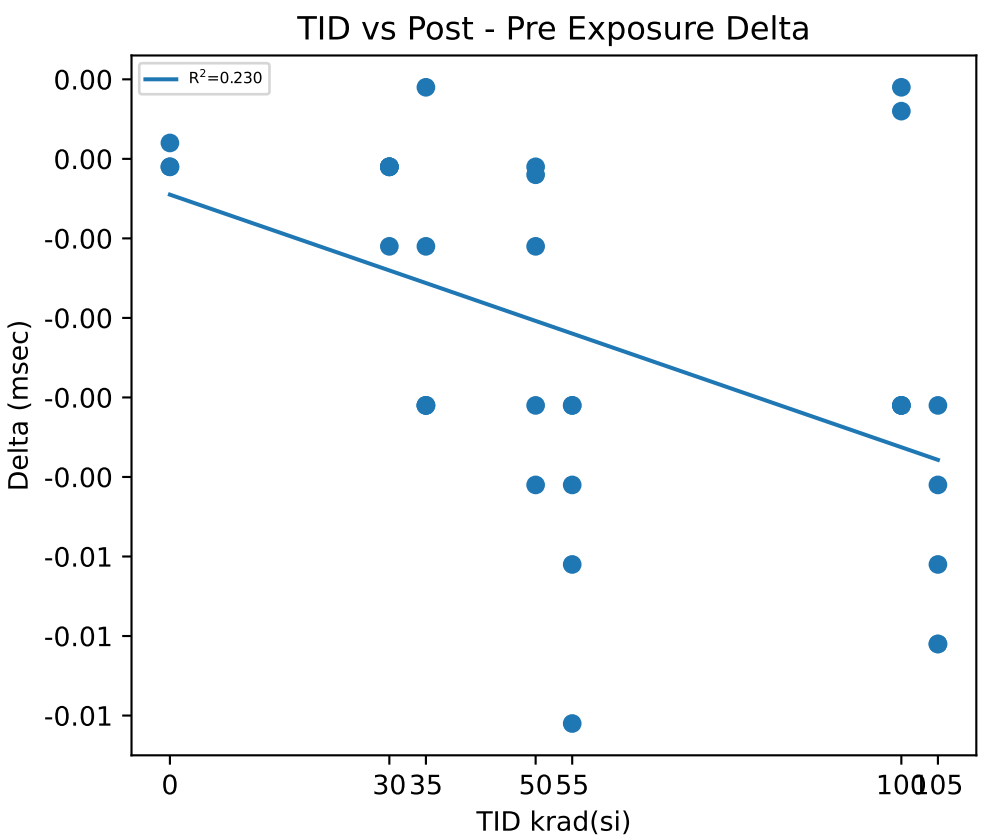
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3156	0.3156	0
2	0	CU2	0.3257	0.3256	-0.0001
3	0	CU3	0.3177	0.3206	0.0029
11	30	Unbiased-30krad	0.3207	0.3206	-0.0001
12	30	Unbiased-30krad	0.3267	0.3266	-0.0001
13	30	Unbiased-30krad	0.3227	0.3196	-0.0031
14	30	Unbiased-30krad	0.3237	0.3206	-0.0031
15	30	Unbiased-30krad	0.3147	0.3156	0.0009
16	35	Biased-30krad	0.3257	0.3256	-0.0001
17	35	Biased-30krad	0.3197	0.3146	-0.0051
18	35	Biased-30krad	0.3227	0.3186	-0.0041
19	35	Biased-30krad	0.3207	0.3216	0.0009
20	35	Biased-30krad	0.3347	0.3346	-0.0001
30	50	Unbiased-50krad	0.3287	0.3236	-0.0051
31	50	Unbiased-50krad	0.3237	0.3236	-0.0001
32	50	Unbiased-50krad	0.3297	0.3266	-0.0031
33	50	Unbiased-50krad	0.3267	0.3256	-0.0011
34	50	Unbiased-50krad	0.3297	0.3296	-0.0001
40	55	Biased-50krad	0.3287	0.3216	-0.0071
41	55	Biased-50krad	0.3257	0.3226	-0.0031
42	55	Biased-50krad	0.3285	0.3226	-0.0059
43	55	Biased-50krad	0.3317	0.3266	-0.0051
44	55	Biased-50krad	0.3277	0.3224	-0.0053
45	100	Unbiased-100krad	0.3287	0.3276	-0.0011
46	100	Unbiased-100krad	0.3267	0.3226	-0.0041
47	100	Unbiased-100krad	0.3317	0.3276	-0.0041
48	100	Unbiased-100krad	0.3267	0.3266	-0.0001
49	100	Unbiased-100krad	0.3347	0.3336	-0.0011
50	105	Biased-100krad	0.3267	0.3236	-0.0031
51	105	Biased-100krad	0.3277	0.3216	-0.0061
52	105	Biased-100krad	0.3287	0.3226	-0.0061
53	105	Biased-100krad	0.3247	0.3186	-0.0061
54	105	Biased-100krad	0.3267	0.3206	-0.0061

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3156	0.31967	0.3257	0.0053295	0.3156	0.3206	0.3256	0.005	-0.0001	0.00093333	0.0029	0.0017039
30	0.3147	0.3217	0.3267	0.0044721	0.3156	0.3206	0.3266	0.003937	-0.0031	-0.0011	0.0009	0.0018708
35	0.3197	0.3247	0.3347	0.0060415	0.3146	0.323	0.3346	0.0076354	-0.0051	-0.0017	0.0009	0.0027019
50	0.3237	0.3277	0.3297	0.0025495	0.3236	0.3258	0.3296	0.00249	-0.0051	-0.0019	-0.0001	0.0021679
55	0.3257	0.32846	0.3317	0.0021652	0.3216	0.32316	0.3266	0.0019667	-0.0071	-0.0053	-0.0031	0.001456
100	0.3267	0.3297	0.3347	0.0034641	0.3226	0.3276	0.3336	0.003937	-0.0041	-0.0021	-0.0001	0.0018708
105	0.3247	0.3269	0.3287	0.0014832	0.3186	0.3214	0.3236	0.0019235	-0.0061	-0.0055	-0.0031	0.0013416

Device Test: 36.3 _EnableDelay|EnRisingToSwRising/EN3/7/7///90.9/634//0///@T_ENABLE_DELAY_VIN





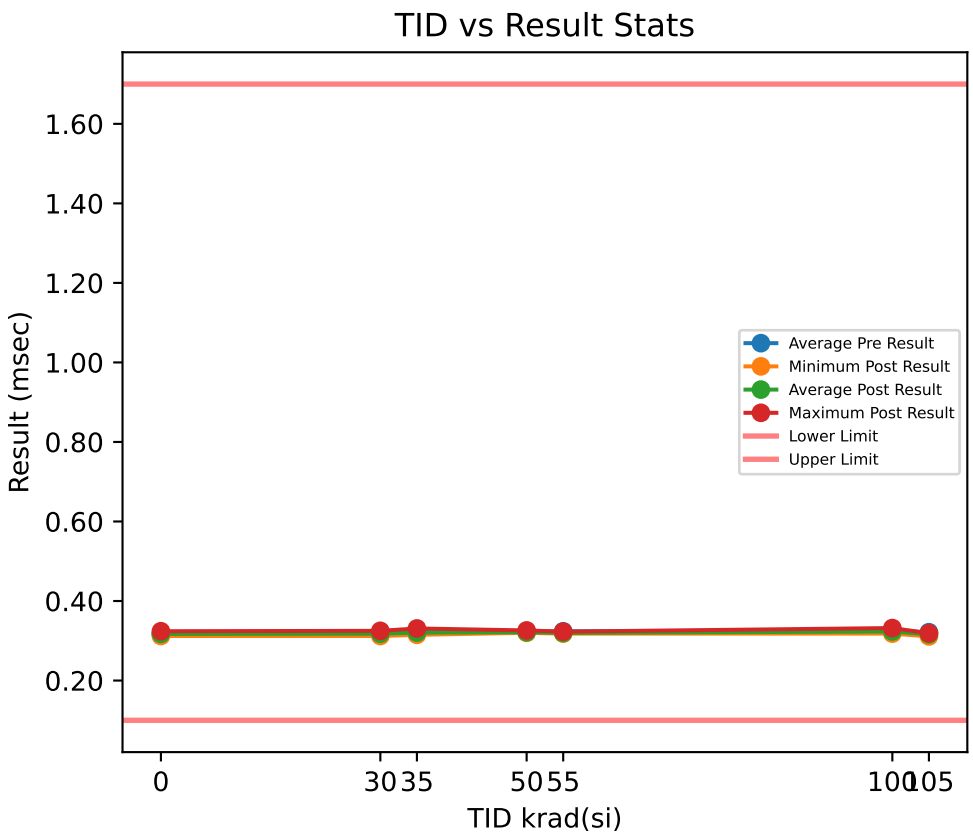
Test Results (Lower Limit = 0.1, Upper Limit = 1.7 (msec))

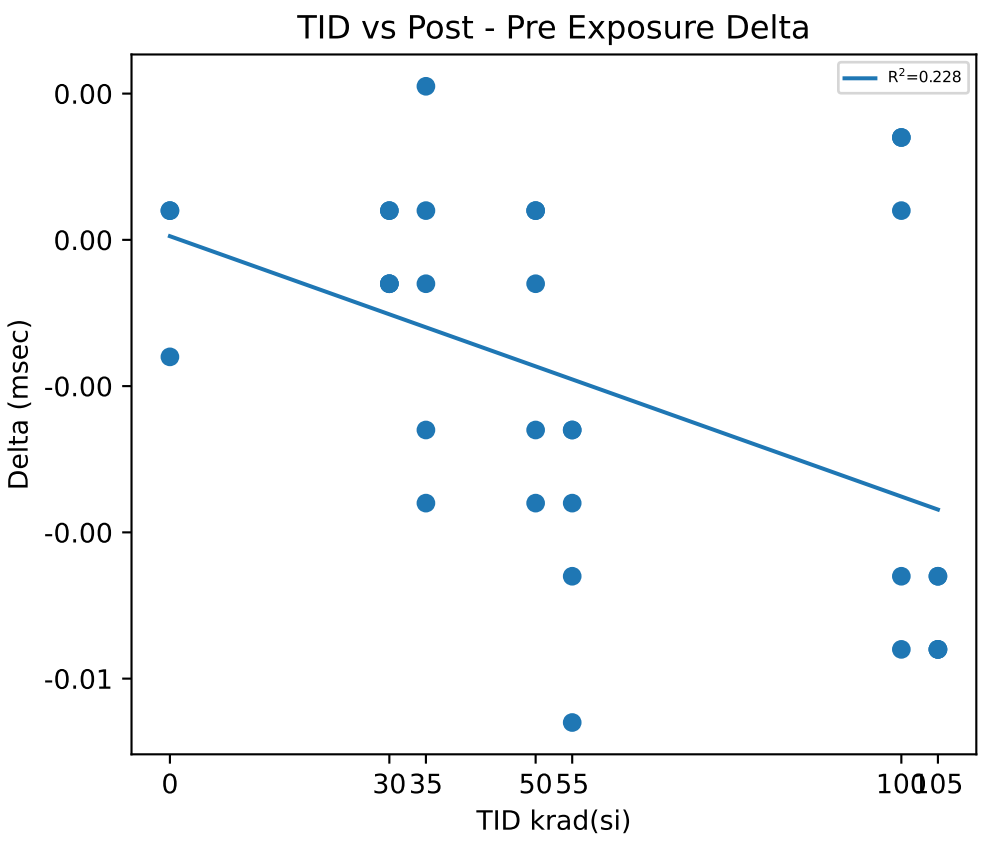
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3109	0.3108	-0.0001
2	0	CU2	0.3189	0.3191	0.0002
3	0	CU3	0.3149	0.3148	-0.0001
11	30	Unbiased-30krad	0.3169	0.3168	-0.0001
12	30	Unbiased-30krad	0.3239	0.3238	-0.0001
13	30	Unbiased-30krad	0.3169	0.3168	-0.0001
14	30	Unbiased-30krad	0.3229	0.3218	-0.0011
15	30	Unbiased-30krad	0.3099	0.3098	-0.0001
16	35	Biased-30krad	0.3249	0.3238	-0.0011
17	35	Biased-30krad	0.3169	0.3138	-0.0031
18	35	Biased-30krad	0.3169	0.3138	-0.0031
19	35	Biased-30krad	0.3169	0.3178	0.0009
20	35	Biased-30krad	0.3339	0.3308	-0.0031
30	50	Unbiased-50krad	0.3259	0.3228	-0.0031
31	50	Unbiased-50krad	0.3229	0.3228	-0.0001
32	50	Unbiased-50krad	0.3249	0.3208	-0.0041
33	50	Unbiased-50krad	0.3199	0.3188	-0.0011
34	50	Unbiased-50krad	0.326	0.3258	-0.0002
40	55	Biased-50krad	0.3249	0.3178	-0.0071
41	55	Biased-50krad	0.3249	0.3218	-0.0031
42	55	Biased-50krad	0.3229	0.3198	-0.0031
43	55	Biased-50krad	0.3299	0.3258	-0.0041
44	55	Biased-50krad	0.3219	0.3168	-0.0051
45	100	Unbiased-100krad	0.3259	0.3268	0.0009
46	100	Unbiased-100krad	0.3239	0.3208	-0.0031
47	100	Unbiased-100krad	0.3279	0.3248	-0.0031
48	100	Unbiased-100krad	0.3239	0.3208	-0.0031
49	100	Unbiased-100krad	0.3299	0.3305	0.0006
50	105	Biased-100krad	0.3199	0.3158	-0.0041
51	105	Biased-100krad	0.3239	0.3178	-0.0061
52	105	Biased-100krad	0.3229	0.3198	-0.0031
53	105	Biased-100krad	0.3189	0.3138	-0.0051
54	105	Biased-100krad	0.3229	0.3168	-0.0061

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3109	0.3149	0.3189	0.004	0.3108	0.3149	0.3191	0.0041509	-0.0001	0	0.0002	0.00017321
30	0.3099	0.3181	0.3239	0.0056303	0.3098	0.3178	0.3238	0.0054314	-0.0011	-0.0003	-0.0001	0.00044721
35	0.3169	0.3219	0.3339	0.0075498	0.3138	0.32	0.3308	0.0072938	-0.0031	-0.0019	0.0009	0.0017889
50	0.3199	0.32392	0.326	0.0025694	0.3188	0.3222	0.3258	0.0026077	-0.0041	-0.00172	-0.0001	0.001795
55	0.3219	0.3249	0.3299	0.0030822	0.3168	0.3204	0.3258	0.0035777	-0.0071	-0.0045	-0.0031	0.0016733
100	0.3239	0.3263	0.3299	0.0026077	0.3208	0.32474	0.3305	0.0041374	-0.0031	-0.00156	0.0009	0.0021114
105	0.3189	0.3217	0.3239	0.0021679	0.3138	0.3168	0.3198	0.0022361	-0.0061	-0.0049	-0.0031	0.0013038

Device Test: 36.4 _EnableDelay|EnRisingToSwRising/EN4/7/7///90.9/634//0///@T_ENABLE_DELAY_VIN





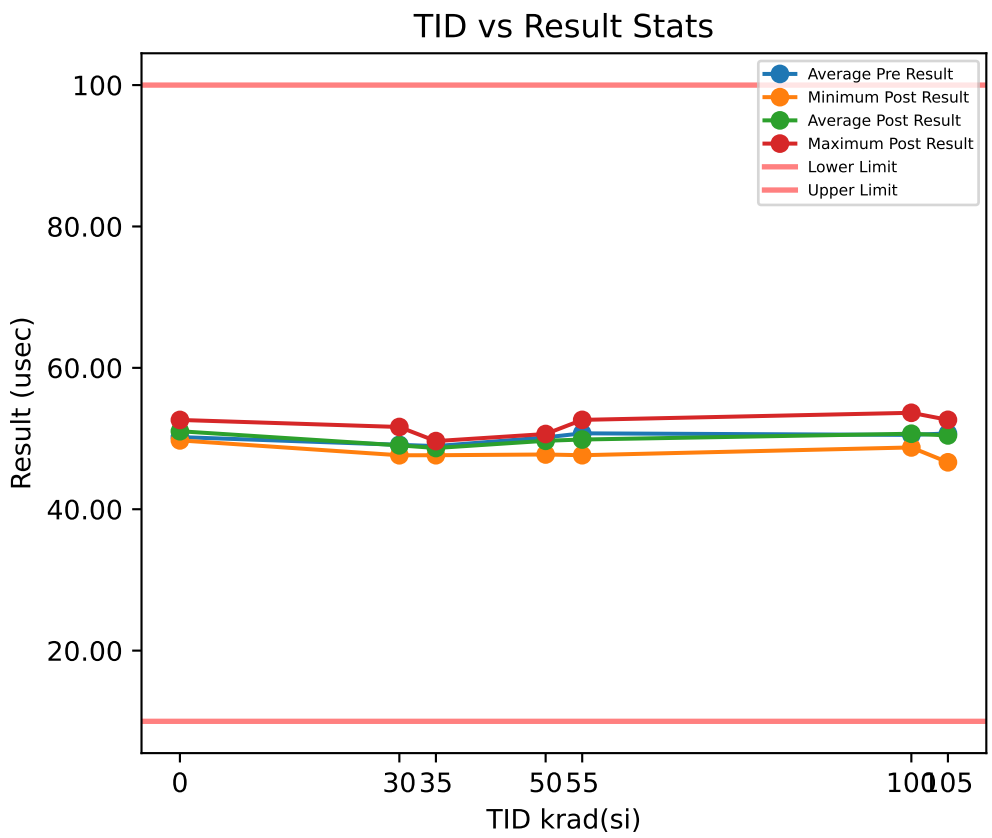
Test Results (Lower Limit = 0.1, Upper Limit = 1.7 (msec))

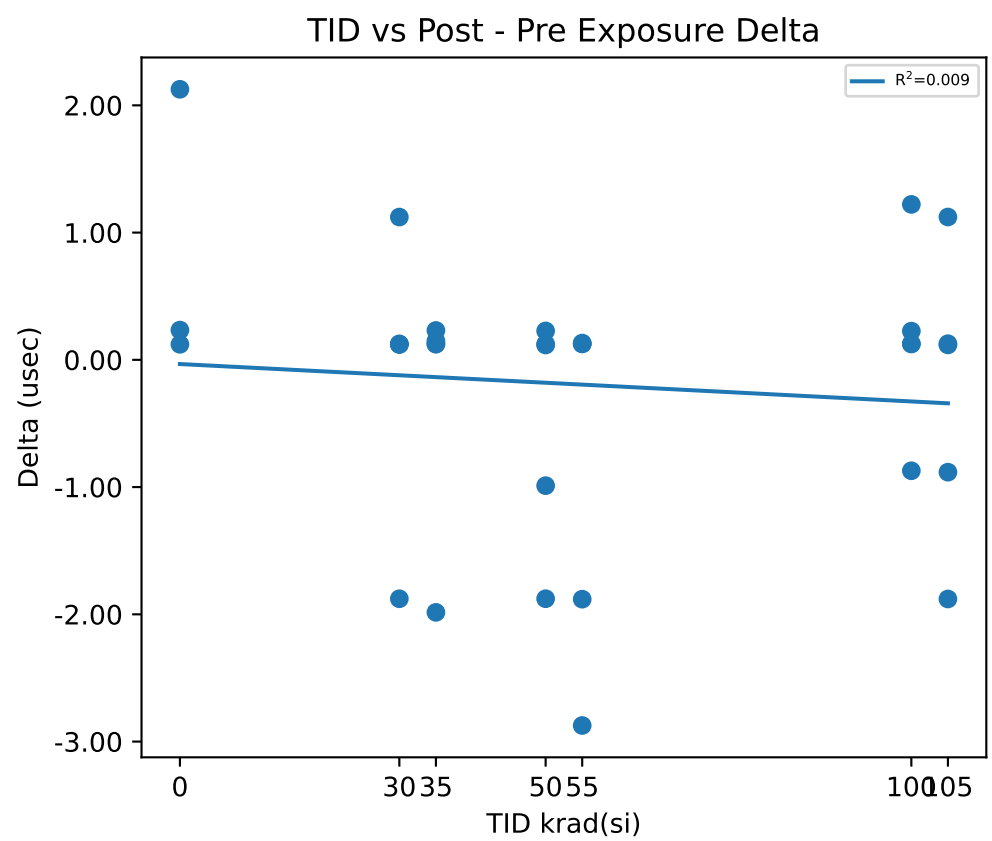
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3136	0.312	-0.0016
2	0	CU2	0.3236	0.324	0.0004
3	0	CU3	0.3156	0.316	0.0004
11	30	Unbiased-30krad	0.3166	0.317	0.0004
12	30	Unbiased-30krad	0.3246	0.325	0.0004
13	30	Unbiased-30krad	0.3186	0.318	-0.0006
14	30	Unbiased-30krad	0.3176	0.317	-0.0006
15	30	Unbiased-30krad	0.3126	0.312	-0.0006
16	35	Biased-30krad	0.3246	0.324	-0.0006
17	35	Biased-30krad	0.3176	0.315	-0.0026
18	35	Biased-30krad	0.3186	0.315	-0.0036
19	35	Biased-30krad	0.3156	0.3177	0.0021
20	35	Biased-30krad	0.3306	0.331	0.0004
30	50	Unbiased-50krad	0.3226	0.32	-0.0026
31	50	Unbiased-50krad	0.3196	0.32	0.0004
32	50	Unbiased-50krad	0.3236	0.32	-0.0036
33	50	Unbiased-50krad	0.3226	0.322	-0.0006
34	50	Unbiased-50krad	0.3256	0.326	0.0004
40	55	Biased-50krad	0.3246	0.318	-0.0066
41	55	Biased-50krad	0.3216	0.319	-0.0026
42	55	Biased-50krad	0.3236	0.321	-0.0026
43	55	Biased-50krad	0.3266	0.323	-0.0036
44	55	Biased-50krad	0.3226	0.318	-0.0046
45	100	Unbiased-100krad	0.3226	0.324	0.0014
46	100	Unbiased-100krad	0.3226	0.318	-0.0046
47	100	Unbiased-100krad	0.3276	0.322	-0.0056
48	100	Unbiased-100krad	0.3206	0.321	0.0004
49	100	Unbiased-100krad	0.3306	0.332	0.0014
50	105	Biased-100krad	0.3246	0.319	-0.0056
51	105	Biased-100krad	0.3236	0.318	-0.0056
52	105	Biased-100krad	0.3226	0.317	-0.0056
53	105	Biased-100krad	0.3156	0.311	-0.0046
54	105	Biased-100krad	0.3216	0.317	-0.0046

Test Statistics (msec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3136	0.3176	0.3236	0.0052915	0.312	0.31733	0.324	0.0061101	-0.0016	-0.00026667	0.0004	0.0011547
30	0.3126	0.318	0.3246	0.0043359	0.312	0.3178	0.325	0.0046583	-0.0006	-0.0002	0.0004	0.00054772
35	0.3156	0.3214	0.3306	0.00614	0.315	0.32054	0.331	0.0069071	-0.0036	-0.00086	0.0021	0.0022887
50	0.3196	0.3228	0.3256	0.0021679	0.32	0.3216	0.326	0.0026077	-0.0036	-0.0012	0.0004	0.0018166
55	0.3216	0.3238	0.3266	0.0019235	0.318	0.3198	0.323	0.0021679	-0.0066	-0.004	-0.0026	0.0016733
100	0.3206	0.3248	0.3306	0.0041473	0.318	0.3234	0.332	0.0052726	-0.0056	-0.0014	0.0014	0.0034205
105	0.3156	0.3216	0.3246	0.0035355	0.311	0.3164	0.319	0.0031305	-0.0056	-0.0052	-0.0046	0.00054772

Device Test: 36.5 _EnableDelay|EnRisingToSwRising/EN1/7/7///90.9/634//0///@T_ENABLE_DELAY





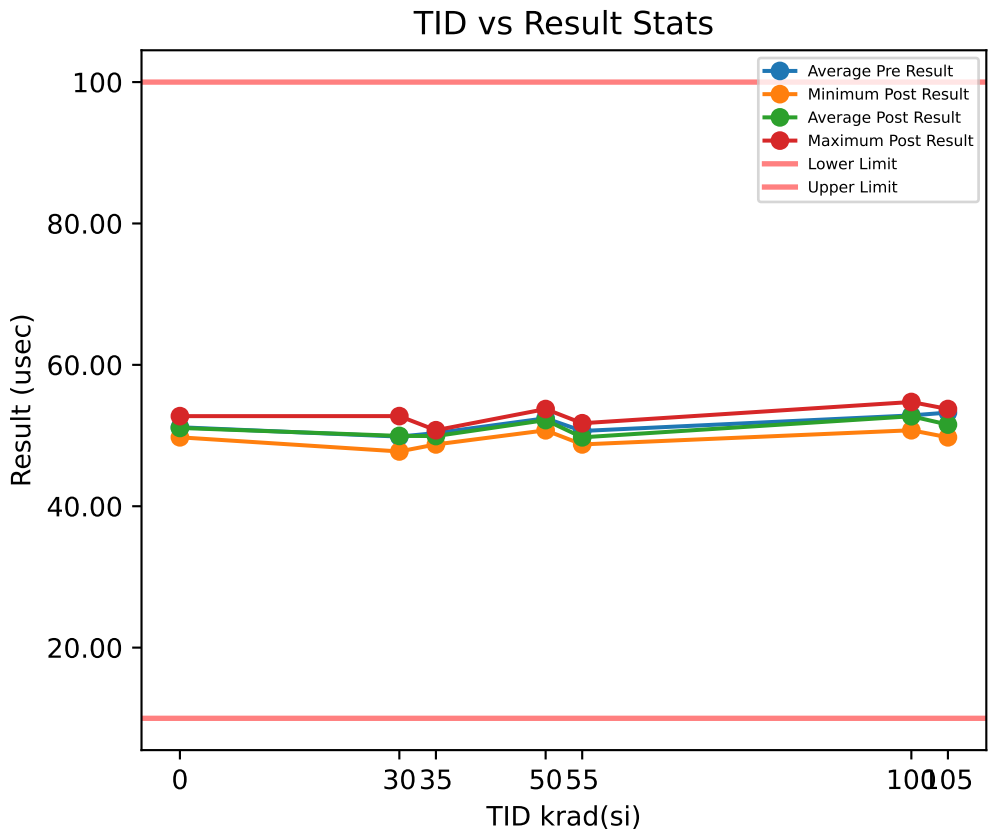
Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

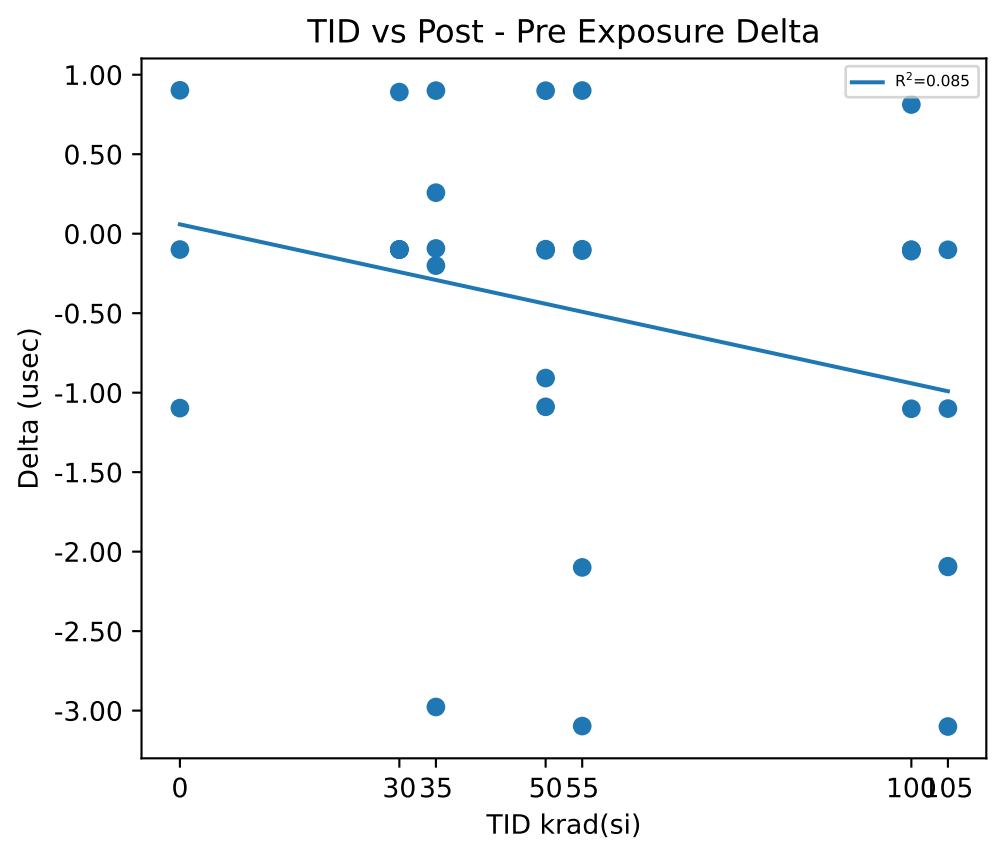
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	48.606	50.732	2.1262
2	0	CU2	49.505	49.739	0.2338
3	0	CU3	52.509	52.631	0.122
11	30	Unbiased-30krad	50.512	51.635	1.1221
12	30	Unbiased-30krad	49.512	47.635	-1.8777
13	30	Unbiased-30krad	47.517	47.638	0.1205
14	30	Unbiased-30krad	49.514	49.639	0.1252
15	30	Unbiased-30krad	48.515	48.638	0.123
16	35	Biased-30krad	49.514	49.638	0.1241
17	35	Biased-30krad	47.514	47.745	0.2308
18	35	Biased-30krad	49.49	49.639	0.1486
19	35	Biased-30krad	48.515	48.639	0.124
20	35	Biased-30krad	49.624	47.64	-1.9846
30	50	Unbiased-50krad	49.516	49.743	0.2272
31	50	Unbiased-50krad	50.524	50.641	0.1165
32	50	Unbiased-50krad	49.516	49.64	0.124
33	50	Unbiased-50krad	51.627	50.639	-0.9887
34	50	Unbiased-50krad	49.621	47.744	-1.8773
40	55	Biased-50krad	50.62	47.747	-2.8737
41	55	Biased-50krad	50.509	50.641	0.1319
42	55	Biased-50krad	47.515	47.641	0.1258
43	55	Biased-50krad	50.515	50.641	0.1258
44	55	Biased-50krad	54.521	52.64	-1.881
45	100	Unbiased-100krad	50.515	50.64	0.1247
46	100	Unbiased-100krad	54.514	53.642	-0.8718
47	100	Unbiased-100krad	50.515	50.641	0.1263
48	100	Unbiased-100krad	48.516	48.742	0.2256
49	100	Unbiased-100krad	48.516	49.738	1.2215
50	105	Biased-100krad	47.523	46.64	-0.8829
51	105	Biased-100krad	51.518	52.641	1.1225
52	105	Biased-100krad	52.519	52.646	0.1268
53	105	Biased-100krad	52.524	52.641	0.1173
54	105	Biased-100krad	49.52	47.641	-1.8794

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.606	50.207	52.509	2.044	49.739	51.034	52.631	1.4696	0.122	0.82733	2.1262	1.1262
30	47.517	49.114	50.512	1.1384	47.635	49.037	51.635	1.6728	-1.8777	-0.07738	1.1221	1.0955
35	47.514	48.931	49.624	0.91038	47.64	48.66	49.639	0.97382	-1.9846	-0.27142	0.2308	0.9587
50	49.516	50.161	51.627	0.92282	47.744	49.681	50.641	1.1829	-1.8773	-0.47966	0.2272	0.92628
55	47.515	50.736	54.521	2.4905	47.641	49.862	52.64	2.141	-2.8737	-0.87424	0.1319	1.4163
100	48.516	50.515	54.514	2.4485	48.742	50.68	53.642	1.8318	-0.8718	0.16526	1.2215	0.74127
105	47.523	50.721	52.524	2.1674	46.64	50.442	52.646	3.0344	-1.8794	-0.27914	1.1225	1.1415

Device Test: 36.6 _EnableDelay|EnRisingToSwRising/EN2/7/7///90.9/634//0///@T_ENABLE_DELAY





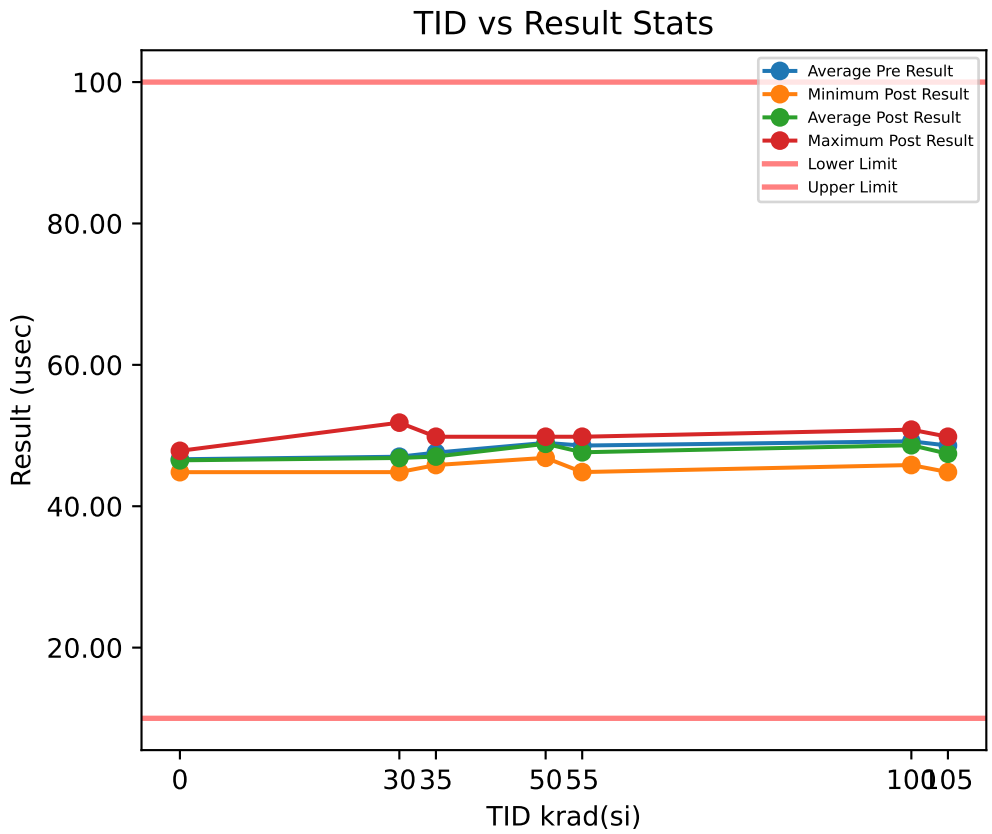
Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

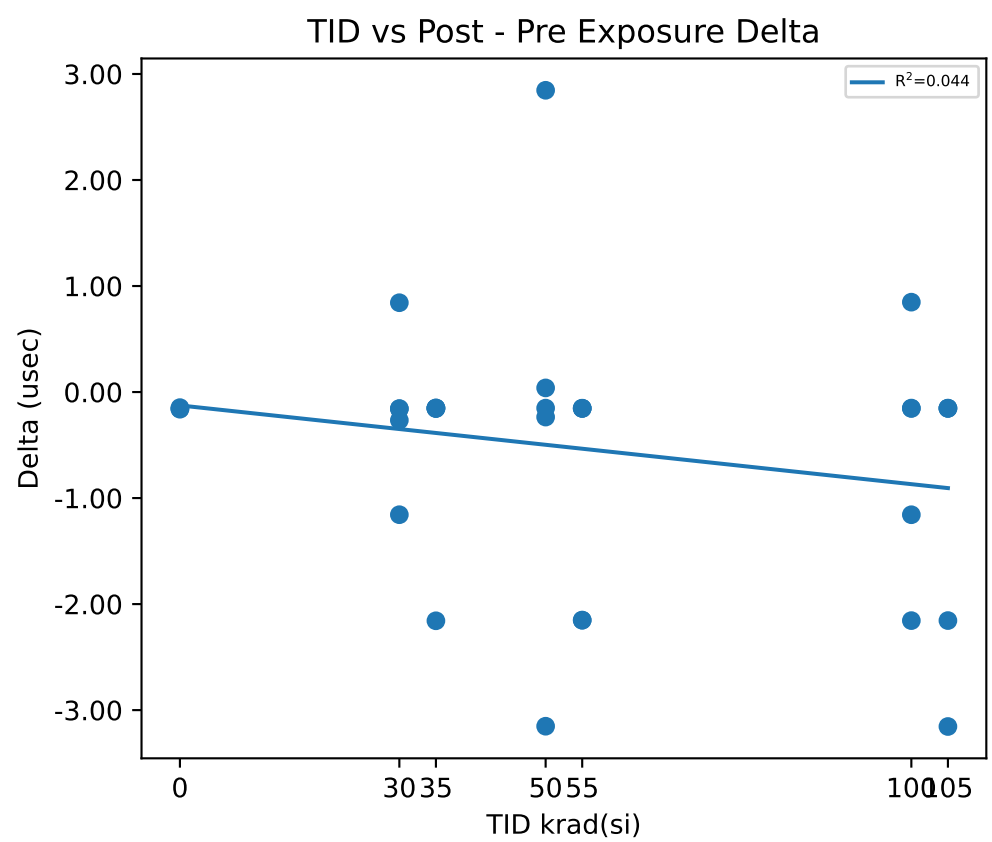
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	49.833	50.735	0.9021
2	0	CU2	52.844	52.744	-0.0997
3	0	CU3	50.847	49.75	-1.0971
11	30	Unbiased-30krad	48.849	48.751	-0.0987
12	30	Unbiased-30krad	47.848	47.748	-0.0996
13	30	Unbiased-30krad	47.852	48.743	0.891
14	30	Unbiased-30krad	52.849	52.749	-0.0999
15	30	Unbiased-30krad	51.846	51.746	-0.1
16	35	Biased-30krad	49.846	49.645	-0.201
17	35	Biased-30krad	48.485	48.743	0.258
18	35	Biased-30krad	49.848	50.748	0.9
19	35	Biased-30krad	49.846	49.753	-0.0928
20	35	Biased-30krad	53.729	50.752	-2.9772
30	50	Unbiased-50krad	52.847	52.742	-0.1051
31	50	Unbiased-50krad	51.851	50.943	-0.9081
32	50	Unbiased-50krad	52.846	52.749	-0.0973
33	50	Unbiased-50krad	54.837	53.748	-1.089
34	50	Unbiased-50krad	49.841	50.74	0.8995
40	55	Biased-50krad	51.842	48.745	-3.0973
41	55	Biased-50krad	48.849	48.751	-0.0977
42	55	Biased-50krad	47.848	48.749	0.9005
43	55	Biased-50krad	51.846	51.74	-0.1065
44	55	Biased-50krad	52.851	50.752	-2.0992
45	100	Unbiased-100krad	53.851	53.749	-0.1017
46	100	Unbiased-100krad	54.848	54.747	-0.1012
47	100	Unbiased-100krad	51.849	50.748	-1.1013
48	100	Unbiased-100krad	51.848	51.738	-0.1099
49	100	Unbiased-100krad	51.845	52.657	0.8125
50	105	Biased-100krad	52.85	49.75	-3.1
51	105	Biased-100krad	54.845	52.749	-2.0961
52	105	Biased-100krad	52.843	50.752	-2.0917
53	105	Biased-100krad	54.852	53.752	-1.1002
54	105	Biased-100krad	50.85	50.749	-0.1013

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.833	51.174	52.844	1.5321	49.75	51.076	52.744	1.5261	-1.0971	-0.098233	0.9021	0.9996
30	47.848	49.849	52.849	2.3439	47.748	49.947	52.749	2.168	-0.1	0.09856	0.891	0.44299
35	48.485	50.351	53.729	1.9784	48.743	49.928	50.752	0.8464	-2.9772	-0.4226	0.9	1.4913
50	49.841	52.445	54.837	1.8153	50.74	52.185	53.748	1.2944	-1.089	-0.26	0.8995	0.79091
55	47.848	50.647	52.851	2.1673	48.745	49.747	51.74	1.4119	-3.0973	-0.90004	0.9005	1.6417
100	51.845	52.848	54.848	1.415	50.748	52.728	54.747	1.5829	-1.1013	-0.12032	0.8125	0.677
105	50.85	53.248	54.852	1.6732	49.75	51.55	53.752	1.6438	-3.1	-1.6979	-0.1013	1.1386

Device Test: 36.7 _EnableDelay|EnRisingToSwRising/EN3/7/7///90.9/634//0///@T_ENABLE_DELAY





Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

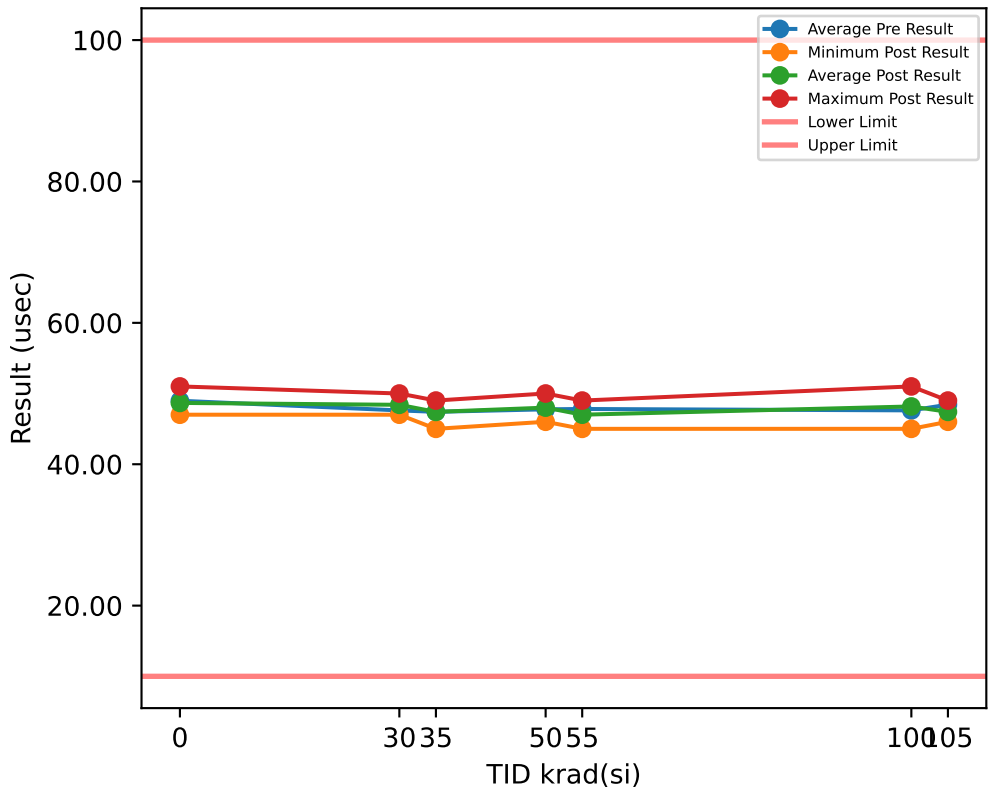
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	44.966	44.819	-0.1469
2	0	CU2	47.997	47.836	-0.1617
3	0	CU3	46.981	46.824	-0.1577
11	30	Unbiased-30krad	46.983	45.826	-1.1569
12	30	Unbiased-30krad	45.091	44.825	-0.2659
13	30	Unbiased-30krad	44.985	44.826	-0.159
14	30	Unbiased-30krad	51.982	51.826	-0.1556
15	30	Unbiased-30krad	45.981	46.824	0.8426
16	35	Biased-30krad	46.979	46.828	-0.1511
17	35	Biased-30krad	47.984	45.827	-2.1574
18	35	Biased-30krad	46.981	46.828	-0.153
19	35	Biased-30krad	45.979	45.829	-0.1501
20	35	Biased-30krad	49.985	49.829	-0.156
30	50	Unbiased-50krad	51.98	48.828	-3.1519
31	50	Unbiased-50krad	50.065	49.829	-0.236
32	50	Unbiased-50krad	48.981	48.83	-0.1515
33	50	Unbiased-50krad	46.81	46.849	0.039
34	50	Unbiased-50krad	46.984	49.83	2.8462
40	55	Biased-50krad	47.984	47.83	-0.1549
41	55	Biased-50krad	49.981	47.83	-2.1513
42	55	Biased-50krad	44.985	44.831	-0.1535
43	55	Biased-50krad	49.982	49.83	-0.152
44	55	Biased-50krad	49.982	47.83	-2.1517
45	100	Unbiased-100krad	49.984	49.83	-0.1549
46	100	Unbiased-100krad	50.983	50.832	-0.1512
47	100	Unbiased-100krad	50.989	49.832	-1.1572
48	100	Unbiased-100krad	44.981	45.828	0.8479
49	100	Unbiased-100krad	48.983	46.827	-2.1558
50	105	Biased-100krad	44.984	44.831	-0.1526
51	105	Biased-100krad	48.981	48.829	-0.1518
52	105	Biased-100krad	49.985	46.83	-3.1546
53	105	Biased-100krad	51.984	49.829	-2.1554
54	105	Biased-100krad	46.984	46.83	-0.1544

Test Statistics (usec)

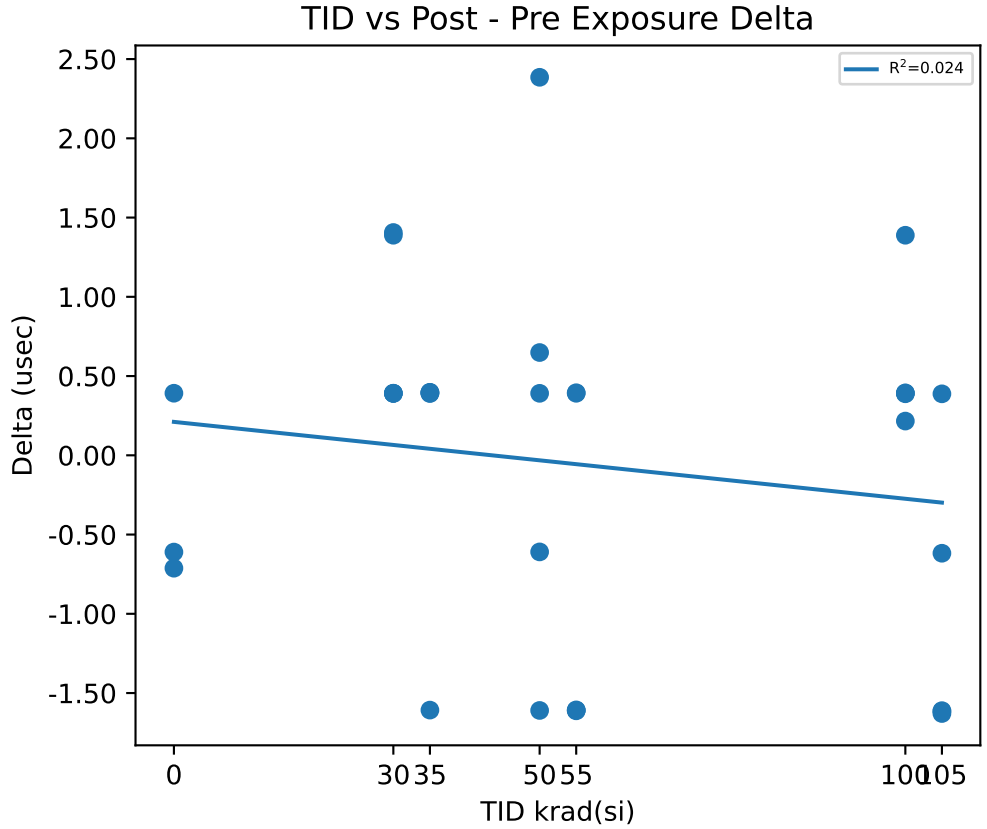
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	44.966	46.648	47.997	1.5427	44.819	46.493	47.836	1.535	-0.1617	-0.15543	-0.1469	0.0076559
30	44.985	47.004	51.982	2.8965	44.825	46.825	51.826	2.9157	-1.1569	-0.17896	0.8426	0.7086
35	45.979	47.582	49.985	1.5191	45.827	47.028	49.829	1.6436	-2.1574	-0.55352	-0.1501	0.8966
50	46.81	48.964	51.98	2.1719	46.849	48.833	49.83	1.2169	-3.1519	-0.13084	2.8462	2.1231
55	44.985	48.583	49.982	2.1896	44.831	47.63	49.83	1.7885	-2.1517	-0.95268	-0.152	1.0944
100	44.981	49.184	50.989	2.4922	45.828	48.63	50.832	2.1698	-2.1558	-0.55424	0.8479	1.142
105	44.984	48.584	51.984	2.702	44.831	47.43	49.829	1.9485	-3.1546	-1.1538	-0.1518	1.4152

Device Test: 36.8 _EnableDelay|EnRisingToSwRising/EN4/7/7///90.9/634//0///@T_ENABLE_DELAY

TID vs Result Stats



TID vs Post - Pre Exposure Delta



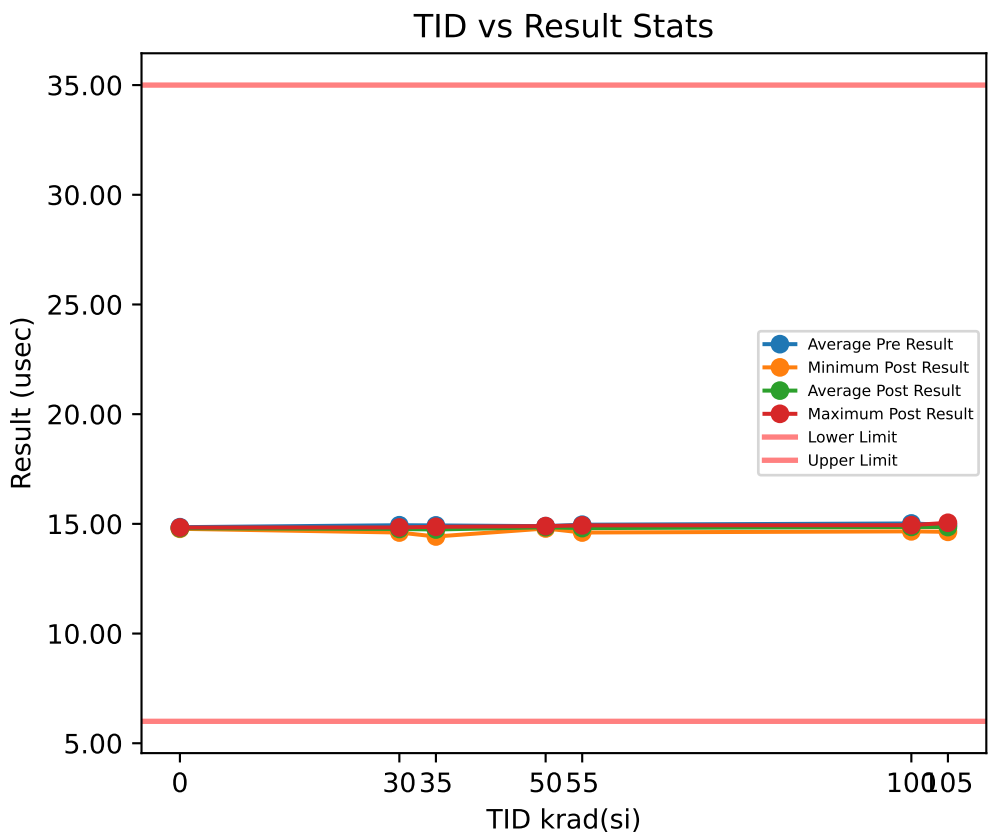
Test Results (Lower Limit = 10.0, Upper Limit = 100.0 (usec))

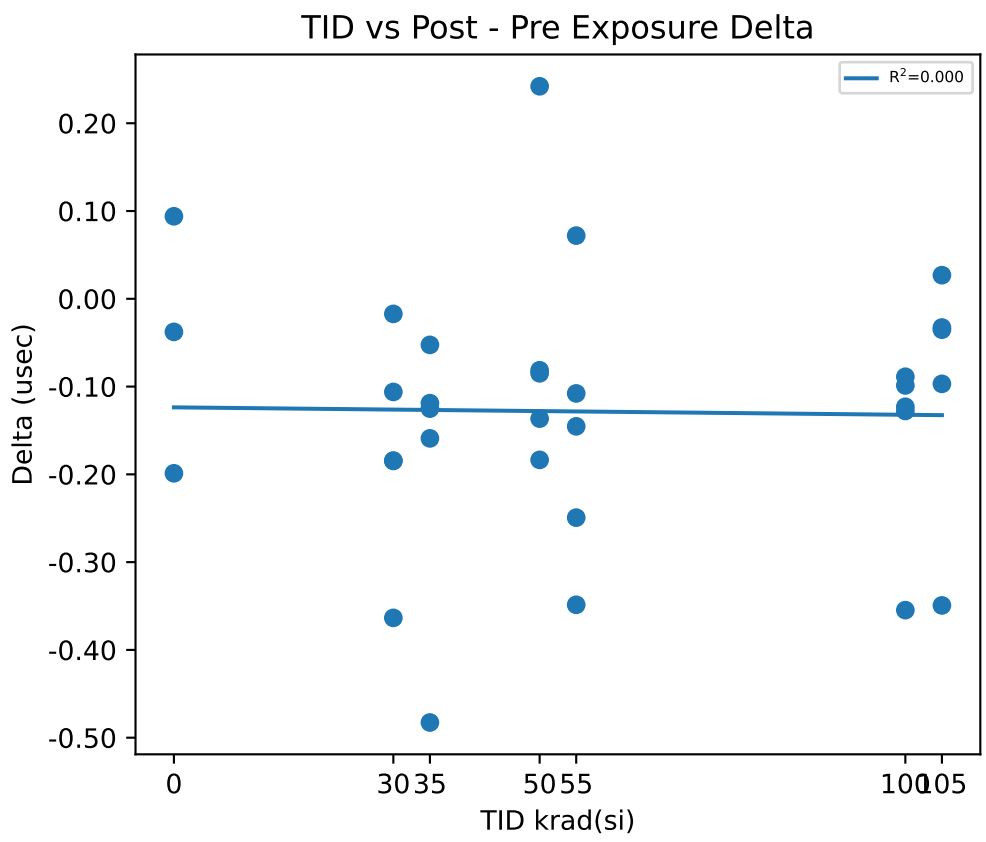
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	47.718	47.006	-0.7123
2	0	CU2	50.614	51.006	0.3917
3	0	CU3	48.616	48.006	-0.6105
11	30	Unbiased-30krad	46.615	47.007	0.3916
12	30	Unbiased-30krad	47.599	49.005	1.4058
13	30	Unbiased-30krad	45.618	47.007	1.3885
14	30	Unbiased-30krad	48.616	49.006	0.3901
15	30	Unbiased-30krad	49.613	50.005	0.3917
16	35	Biased-30krad	47.61	48.008	0.3975
17	35	Biased-30krad	48.619	49.008	0.3898
18	35	Biased-30krad	47.613	46.006	-1.6076
19	35	Biased-30krad	44.61	45.007	0.3968
20	35	Biased-30krad	48.613	49.006	0.3932
30	50	Unbiased-50krad	48.359	49.008	0.6485
31	50	Unbiased-50krad	46.619	47.01	0.3911
32	50	Unbiased-50krad	48.616	48.007	-0.6095
33	50	Unbiased-50krad	47.622	50.007	2.3851
34	50	Unbiased-50krad	47.618	46.008	-1.6098
40	55	Biased-50krad	46.614	47.009	0.3947
41	55	Biased-50krad	46.613	45.007	-1.6064
42	55	Biased-50krad	48.617	47.009	-1.6087
43	55	Biased-50krad	46.617	47.009	0.3914
44	55	Biased-50krad	50.619	49.007	-1.6121
45	100	Unbiased-100krad	46.62	47.009	0.3882
46	100	Unbiased-100krad	50.618	50.834	0.216
47	100	Unbiased-100krad	46.616	47.009	0.3925
48	100	Unbiased-100krad	44.615	45.009	0.3935
49	100	Unbiased-100krad	49.618	51.007	1.3885
50	105	Biased-100krad	48.626	48.008	-0.6179
51	105	Biased-100krad	50.62	49.008	-1.6111
52	105	Biased-100krad	45.622	46.01	0.3879
53	105	Biased-100krad	48.638	47.009	-1.6291
54	105	Biased-100krad	48.623	47.008	-1.6149

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.718	48.983	50.614	1.4824	47.006	48.673	51.006	2.0817	-0.7123	-0.31037	0.3917	0.61013
30	45.618	47.612	49.613	1.5796	47.007	48.406	50.005	1.3407	0.3901	0.79354	1.4058	0.55105
35	44.61	47.413	48.619	1.6454	45.007	47.407	49.008	1.8171	-1.6076	-0.00606	0.3975	0.89529
50	46.619	47.767	48.616	0.78007	46.008	48.008	50.007	1.5805	-1.6098	0.24108	2.3851	1.4945
55	46.613	47.816	50.619	1.7909	45.007	47.008	49.007	1.4144	-1.6121	-0.80822	0.3947	1.0966
100	44.615	47.618	50.618	2.4502	45.009	48.173	51.007	2.6379	0.216	0.55574	1.3885	0.47169
105	45.622	48.426	50.62	1.7888	46.01	47.409	49.008	1.1399	-1.6291	-1.017	0.3879	0.89696

Device Test: 36.9 _EnableDelay|EnFallingToSwFalling/EN1/7/7///90.9/634//0///@T_DISABLE_DELAY





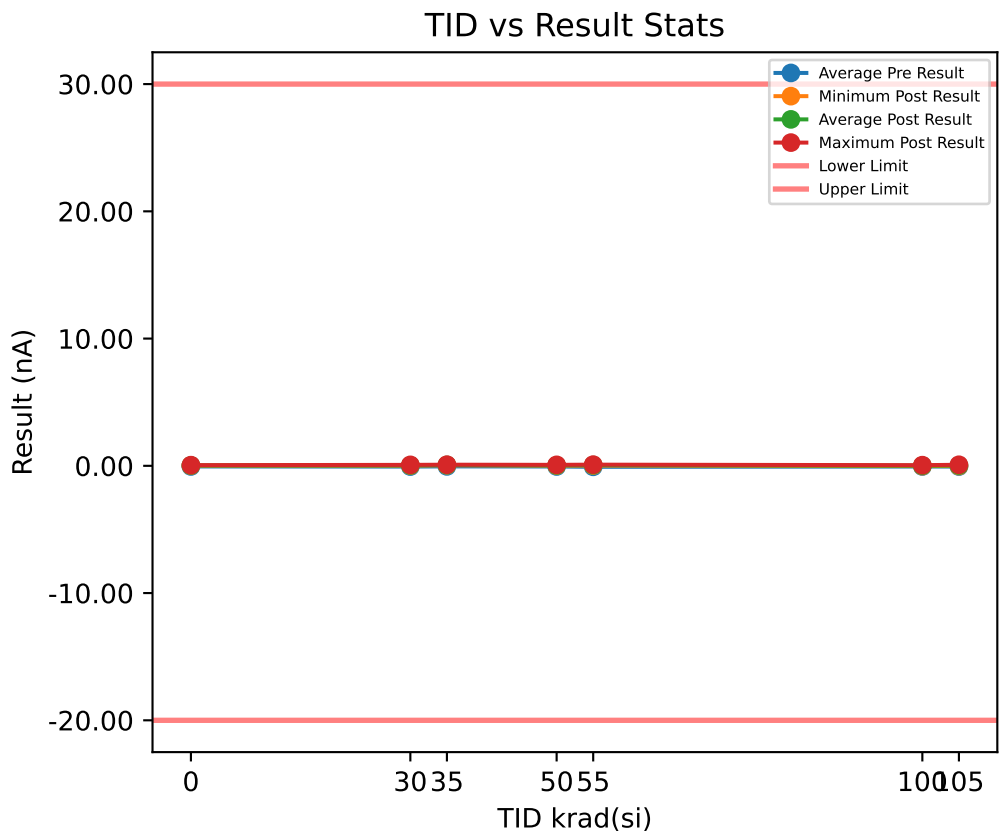
Test Results (Lower Limit = 6.0, Upper Limit = 35.0 (usec))

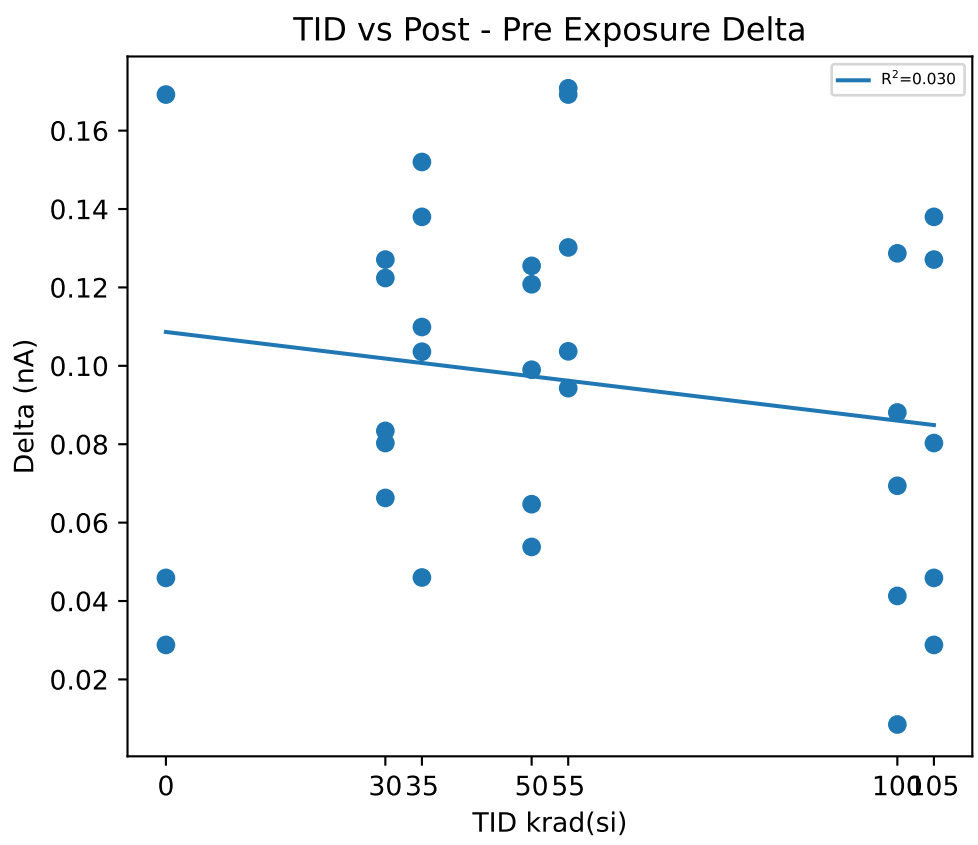
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	14.68	14.774	0.094
2	0	CU2	14.87	14.833	-0.0377
3	0	CU3	14.997	14.798	-0.1988
11	30	Unbiased-30krad	14.978	14.794	-0.1843
12	30	Unbiased-30krad	15.012	14.828	-0.1847
13	30	Unbiased-30krad	14.789	14.772	-0.0172
14	30	Unbiased-30krad	14.942	14.836	-0.1061
15	30	Unbiased-30krad	14.968	14.604	-0.3635
16	35	Biased-30krad	14.95	14.825	-0.1251
17	35	Biased-30krad	14.983	14.864	-0.1189
18	35	Biased-30krad	14.864	14.811	-0.0525
19	35	Biased-30krad	14.907	14.424	-0.4827
20	35	Biased-30krad	14.946	14.787	-0.159
30	50	Unbiased-50krad	14.976	14.891	-0.0849
31	50	Unbiased-50krad	14.87	14.789	-0.0814
32	50	Unbiased-50krad	14.976	14.793	-0.1835
33	50	Unbiased-50krad	14.999	14.862	-0.1365
34	50	Unbiased-50krad	14.655	14.897	0.2421
40	55	Biased-50krad	15.014	14.869	-0.1453
41	55	Biased-50krad	15.018	14.769	-0.2493
42	55	Biased-50krad	14.953	14.605	-0.3486
43	55	Biased-50krad	14.784	14.856	0.072
44	55	Biased-50krad	15.038	14.931	-0.1078
45	100	Unbiased-100krad	15.013	14.659	-0.3547
46	100	Unbiased-100krad	15.064	14.941	-0.123
47	100	Unbiased-100krad	15.011	14.883	-0.1278
48	100	Unbiased-100krad	15.001	14.912	-0.0888
49	100	Unbiased-100krad	15.003	14.905	-0.0987
50	105	Biased-100krad	14.932	14.899	-0.0327
51	105	Biased-100krad	15.022	15.049	0.0269
52	105	Biased-100krad	14.986	14.636	-0.3493
53	105	Biased-100krad	15.012	14.977	-0.0352
54	105	Biased-100krad	14.805	14.708	-0.0969

Test Statistics (usec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.68	14.849	14.997	0.15938	14.774	14.802	14.833	0.029524	-0.1988	-0.0475	0.094	0.14665
30	14.789	14.938	15.012	0.086829	14.604	14.767	14.836	0.094465	-0.3635	-0.17116	-0.0172	0.12776
35	14.864	14.93	14.983	0.04596	14.424	14.742	14.864	0.18018	-0.4827	-0.18764	-0.0525	0.1694
50	14.655	14.895	14.999	0.14316	14.789	14.846	14.897	0.052525	-0.1835	-0.04884	0.2421	0.16795
55	14.784	14.962	15.038	0.10434	14.605	14.806	14.931	0.12635	-0.3486	-0.1558	0.072	0.15829
100	15.001	15.018	15.064	0.025881	14.659	14.86	14.941	0.11437	-0.3547	-0.1586	-0.0888	0.11083
105	14.805	14.951	15.022	0.088908	14.636	14.854	15.049	0.17595	-0.3493	-0.09744	0.0269	0.14744

Device Test: 38.1 _EA|Leakage/VSNS1/3/3///90.9/634//0///@IVSNS_LKG





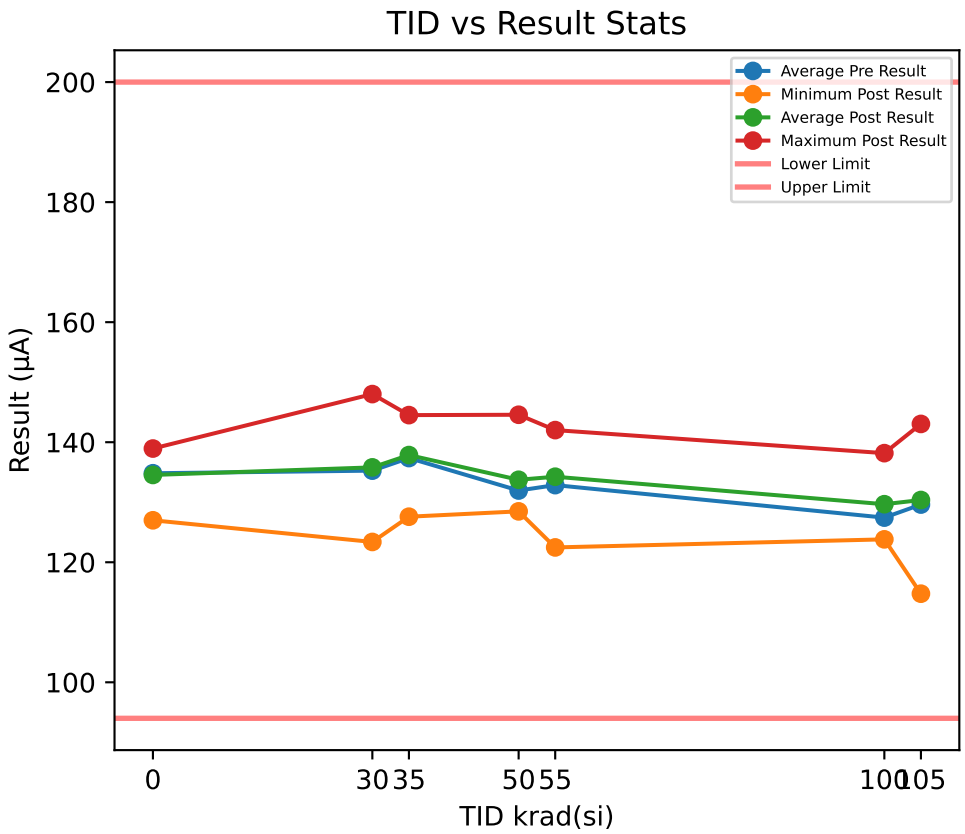
Test Results (Lower Limit = -20.0, Upper Limit = 30.0 (nA))

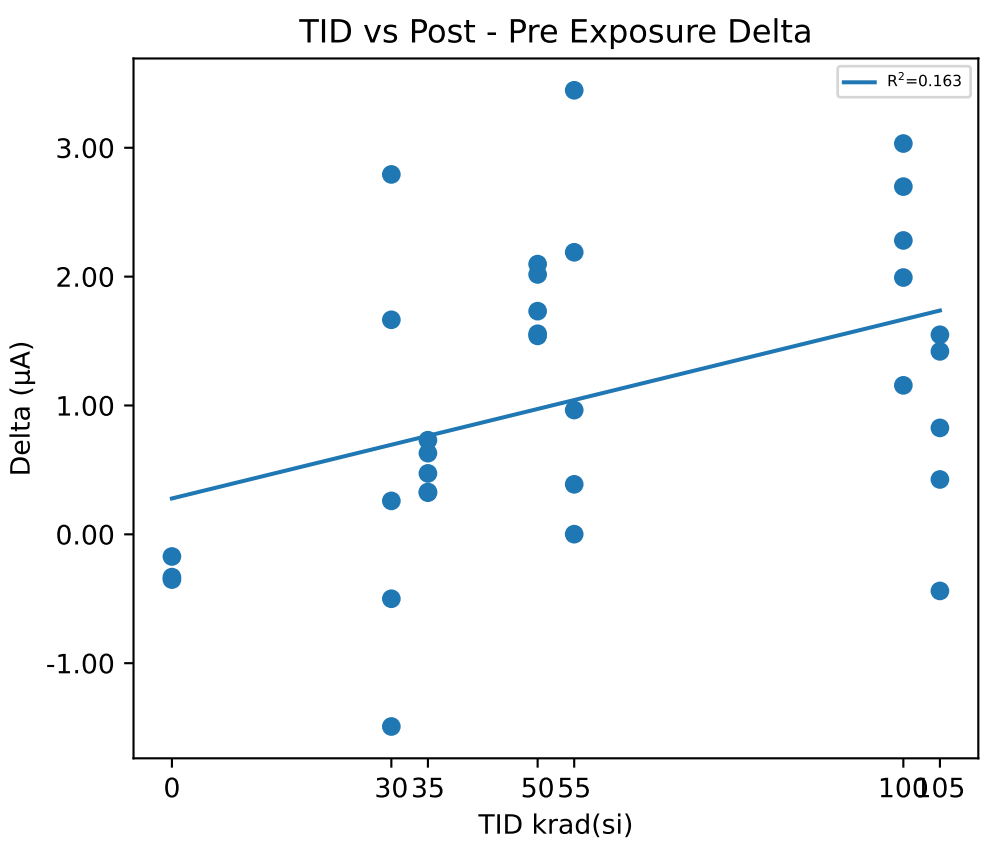
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.0352	0.0107	0.0459
2	0	CU2	0.0038	0.0326	0.0288
3	0	CU3	-0.1179	0.0513	0.1692
11	30	Unbiased-30krad	-0.068	0.0123	0.0803
12	30	Unbiased-30krad	-0.0711	0.0123	0.0834
13	30	Unbiased-30krad	-0.0524	0.0747	0.1271
14	30	Unbiased-30krad	-0.0103	0.056	0.0663
15	30	Unbiased-30krad	-0.093	0.0294	0.1224
16	35	Biased-30krad	-0.0009	0.0451	0.046
17	35	Biased-30krad	-0.0617	0.0419	0.1036
18	35	Biased-30krad	-0.0274	0.0825	0.1099
19	35	Biased-30krad	-0.0633	0.0887	0.152
20	35	Biased-30krad	-0.0742	0.0638	0.138
30	50	Unbiased-50krad	-0.0227	0.0763	0.099
31	50	Unbiased-50krad	-0.0773	0.0482	0.1255
32	50	Unbiased-50krad	-0.029	0.0248	0.0538
33	50	Unbiased-50krad	-0.0851	0.0357	0.1208
34	50	Unbiased-50krad	-0.0524	0.0123	0.0647
40	55	Biased-50krad	-0.0508	0.0529	0.1037
41	55	Biased-50krad	-0.0758	0.0185	0.0943
42	55	Biased-50krad	-0.0914	0.0794	0.1708
43	55	Biased-50krad	-0.1366	0.0326	0.1692
44	55	Biased-50krad	-0.0383	0.0919	0.1302
45	100	Unbiased-100krad	-0.0181	0.0513	0.0694
46	100	Unbiased-100krad	-0.0321	0.0092	0.0413
47	100	Unbiased-100krad	-0.107	-0.0189	0.0881
48	100	Unbiased-100krad	-0.1039	0.0248	0.1287
49	100	Unbiased-100krad	-0.0087	-0.0002	0.0085
50	105	Biased-100krad	-0.121	0.017	0.138
51	105	Biased-100krad	0.0022	0.0825	0.0803
52	105	Biased-100krad	-0.0477	-0.0018	0.0459
53	105	Biased-100krad	-0.0805	0.0466	0.1271
54	105	Biased-100krad	-0.0446	-0.0158	0.0288

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1179	-0.049767	0.0038	0.062144	0.0107	0.031533	0.0513	0.020321	0.0288	0.0813	0.1692	0.076602
30	-0.093	-0.05896	-0.0103	0.030817	0.0123	0.03694	0.0747	0.02766	0.0663	0.0959	0.1271	0.027164
35	-0.0742	-0.0455	-0.0009	0.030495	0.0419	0.0644	0.0887	0.021197	0.046	0.1099	0.152	0.040881
50	-0.0851	-0.0533	-0.0227	0.027906	0.0123	0.03946	0.0763	0.024496	0.0538	0.09276	0.1255	0.032413
55	-0.1366	-0.07858	-0.0383	0.038512	0.0185	0.05506	0.0919	0.030803	0.0943	0.13364	0.1708	0.035712
100	-0.107	-0.05396	-0.0087	0.047748	-0.0189	0.01324	0.0513	0.026515	0.0085	0.0672	0.1287	0.045663
105	-0.121	-0.05832	0.0022	0.045783	-0.0158	0.0257	0.0825	0.039425	0.0288	0.08402	0.138	0.048182

Device Test: 38.10 _EA|SourceCurrent/COMP2/3/3///90.9/634//0///@EA_SOURCE





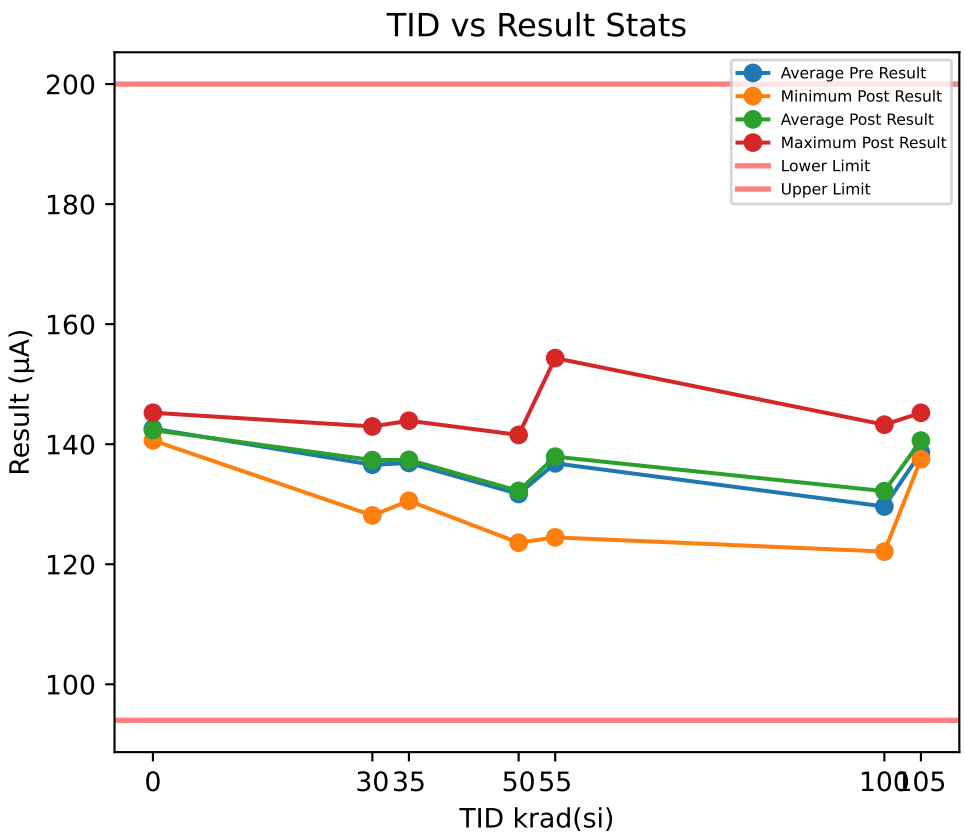
Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

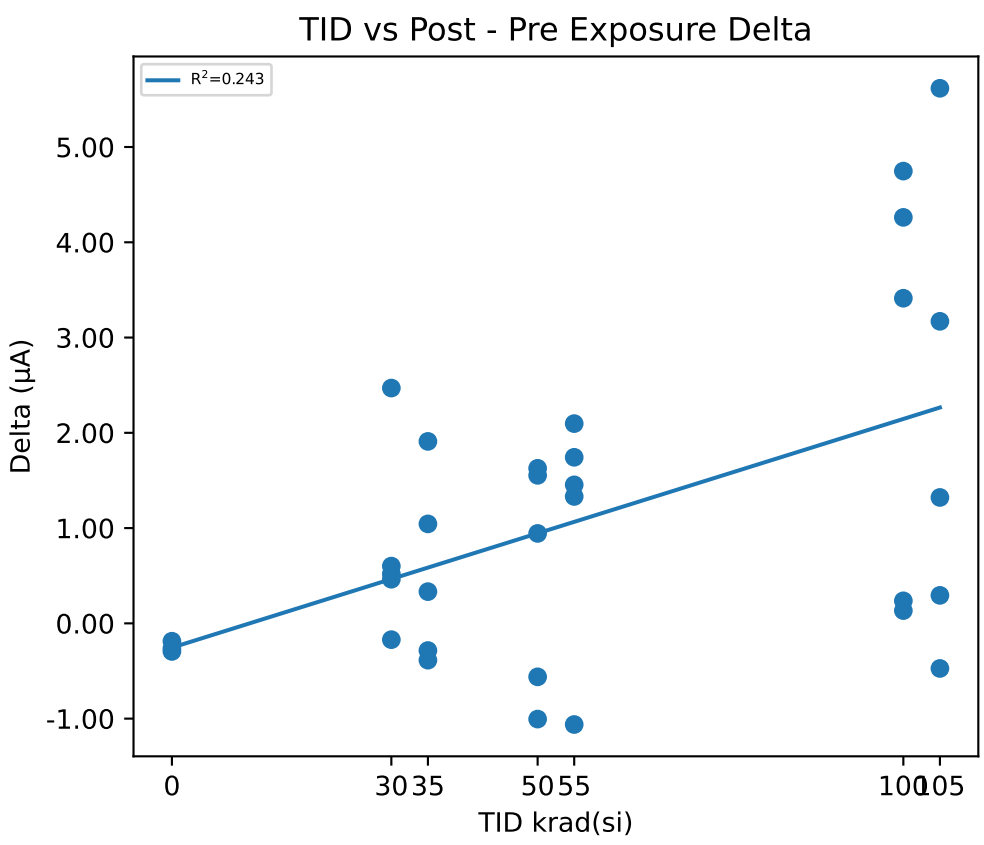
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	139.3	138.95	-0.3512
2	0	CU2	127.16	126.99	-0.1719
3	0	CU3	138.03	137.7	-0.332
11	30	Unbiased-30krad	136.12	135.62	-0.5
12	30	Unbiased-30krad	141.21	139.72	-1.4914
13	30	Unbiased-30krad	145.23	148.02	2.7931
14	30	Unbiased-30krad	121.72	123.38	1.665
15	30	Unbiased-30krad	132.03	132.29	0.2595
16	35	Biased-30krad	135.27	136	0.7307
17	35	Biased-30krad	143.89	144.52	0.63
18	35	Biased-30krad	137.18	137.65	0.473
19	35	Biased-30krad	143.2	143.53	0.3286
20	35	Biased-30krad	127.27	127.59	0.3233
30	50	Unbiased-50krad	126.75	128.48	1.732
31	50	Unbiased-50krad	128.69	130.24	1.5566
32	50	Unbiased-50krad	128.42	130.44	2.0169
33	50	Unbiased-50krad	133.43	134.97	1.5401
34	50	Unbiased-50krad	142.48	144.57	2.0971
40	55	Biased-50krad	129.96	132.15	2.1889
41	55	Biased-50krad	140.84	140.84	0.0012
42	55	Biased-50krad	141.05	142.02	0.9646
43	55	Biased-50krad	130.33	133.77	3.4461
44	55	Biased-50krad	122.08	122.47	0.3881
45	100	Unbiased-100krad	123.37	124.53	1.1563
46	100	Unbiased-100krad	128.53	130.52	1.993
47	100	Unbiased-100krad	129.03	131.31	2.2807
48	100	Unbiased-100krad	135.48	138.18	2.6986
49	100	Unbiased-100krad	120.78	123.82	3.0329
50	105	Biased-100krad	128.55	129.97	1.4198
51	105	Biased-100krad	113.21	114.76	1.5488
52	105	Biased-100krad	132.37	131.93	-0.4392
53	105	Biased-100krad	131.31	132.13	0.826
54	105	Biased-100krad	142.62	143.05	0.4258

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	127.16	134.83	139.3	6.6697	126.99	134.54	138.95	6.5713	-0.3512	-0.28503	-0.1719	0.098446
30	121.72	135.26	145.23	9.0736	123.38	135.81	148.02	9.0997	-1.4914	0.54524	2.7931	1.7051
35	127.27	137.36	143.89	6.7632	127.59	137.86	144.52	6.8082	0.3233	0.49712	0.7307	0.18125
50	126.75	131.95	142.48	6.3871	128.48	133.74	144.57	6.5134	1.5401	1.7885	2.0971	0.25791
55	122.08	132.85	141.05	8.0905	122.47	134.25	142.02	7.8615	0.0012	1.3978	3.4461	1.4124
100	120.78	127.44	135.48	5.6843	123.82	129.67	138.18	5.8427	1.1563	2.2323	3.0329	0.72038
105	113.21	129.61	142.62	10.604	114.76	130.37	143.05	10.124	-0.4392	0.75624	1.5488	0.80802

Device Test: 38.11 _EA|SourceCurrent/COMP3/3/3///90.9/634//0///@EA_SOURCE





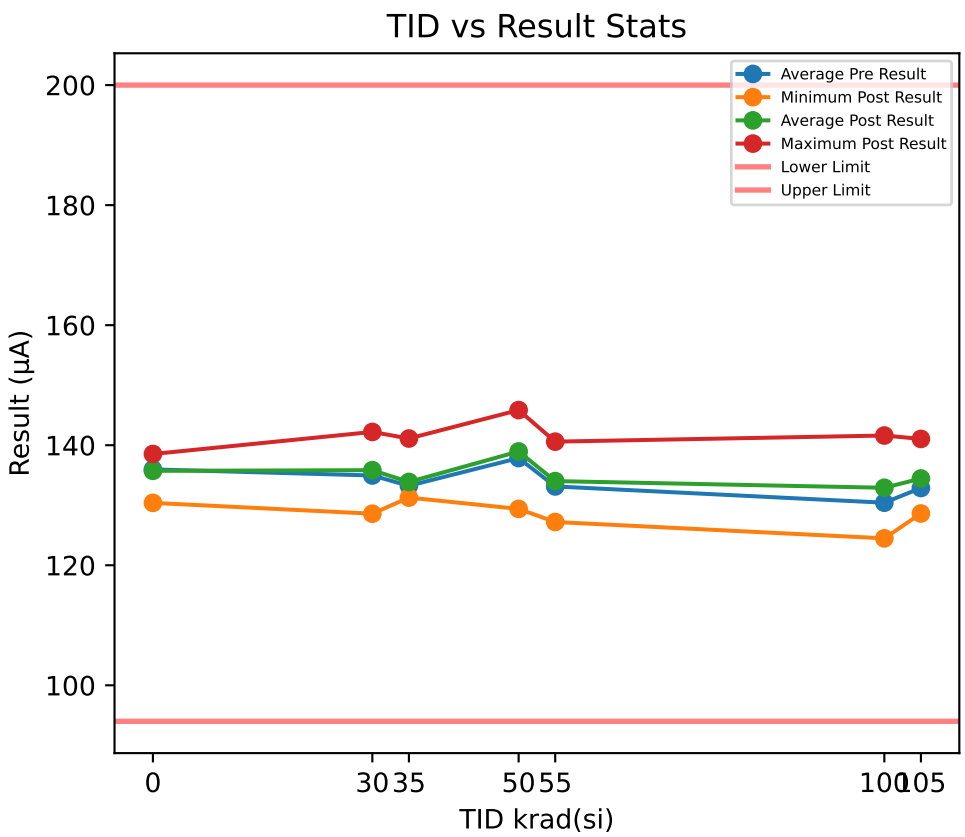
Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

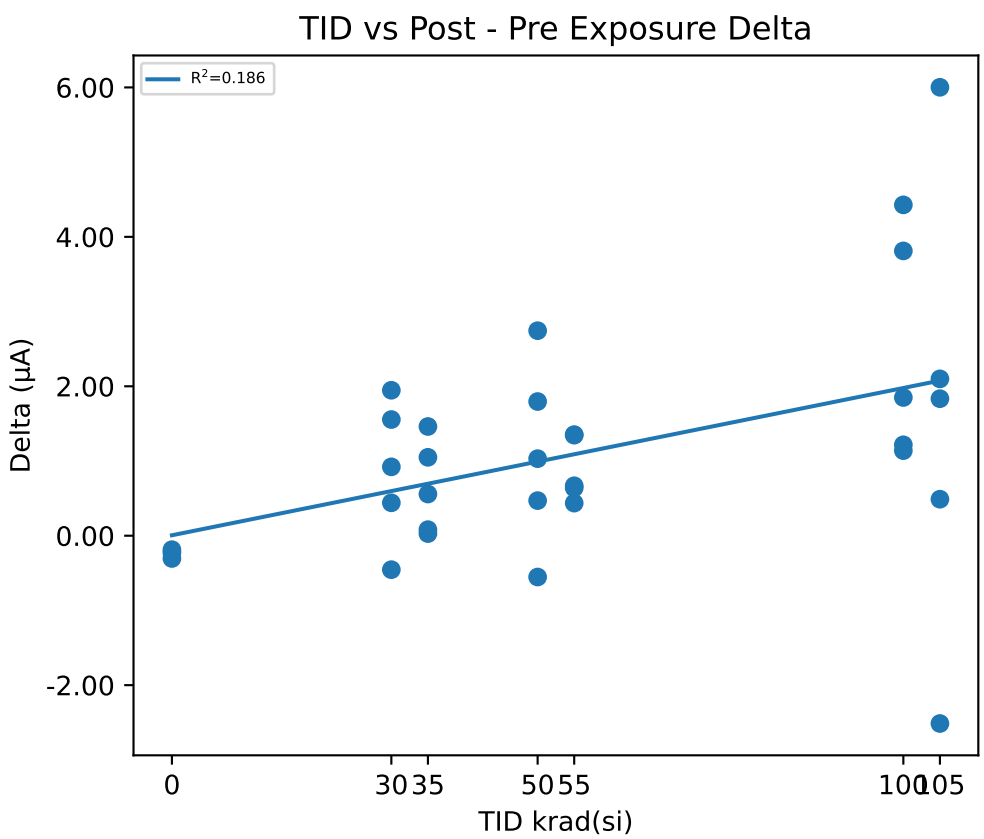
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	145.54	145.24	-0.2947
2	0	CU2	140.9	140.63	-0.2634
3	0	CU3	141.38	141.19	-0.1874
11	30	Unbiased-30krad	140.95	141.47	0.5199
12	30	Unbiased-30krad	135.16	135.62	0.4632
13	30	Unbiased-30krad	137.99	138.59	0.6011
14	30	Unbiased-30krad	125.67	128.14	2.4699
15	30	Unbiased-30krad	143.13	142.96	-0.1711
16	35	Biased-30krad	131.08	130.79	-0.2851
17	35	Biased-30krad	137.5	139.41	1.91
18	35	Biased-30krad	142.87	143.91	1.044
19	35	Biased-30krad	141.96	142.29	0.333
20	35	Biased-30krad	130.95	130.57	-0.3866
30	50	Unbiased-50krad	121.96	123.59	1.6275
31	50	Unbiased-50krad	131.56	133.11	1.5537
32	50	Unbiased-50krad	130.71	129.71	-1.0048
33	50	Unbiased-50krad	132.2	133.15	0.9441
34	50	Unbiased-50krad	142.11	141.55	-0.5613
40	55	Biased-50krad	145.18	146.93	1.7431
41	55	Biased-50krad	131.17	130.11	-1.0617
42	55	Biased-50krad	152.25	154.35	2.0967
43	55	Biased-50krad	123.14	124.48	1.3319
44	55	Biased-50krad	132.32	133.78	1.4539
45	100	Unbiased-100krad	126.5	126.74	0.2365
46	100	Unbiased-100krad	118.7	122.11	3.4127
47	100	Unbiased-100krad	132.44	132.57	0.1342
48	100	Unbiased-100krad	138.51	143.25	4.7471
49	100	Unbiased-100krad	131.96	136.22	4.2614
50	105	Biased-100krad	145.27	144.79	-0.4733
51	105	Biased-100krad	134.32	137.49	3.1704
52	105	Biased-100krad	137.63	137.92	0.2939
53	105	Biased-100krad	131.98	137.59	5.6164
54	105	Biased-100krad	143.91	145.23	1.3217

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	140.9	142.6	145.54	2.5516	140.63	142.36	145.24	2.5157	-0.2947	-0.2485	-0.1874	0.05518
30	125.67	136.58	143.13	6.8023	128.14	137.35	142.96	5.87	-0.1711	0.7766	2.4699	0.99503
35	130.95	136.87	142.87	5.7201	130.57	137.39	143.91	6.3401	-0.3866	0.52306	1.91	0.96329
50	121.96	131.71	142.11	7.1501	123.59	132.22	141.55	6.51	-1.0048	0.51184	1.6275	1.2216
55	123.14	136.81	152.25	11.698	124.48	137.93	154.35	12.35	-1.0617	1.1128	2.0967	1.2508
100	118.7	129.62	138.51	7.4403	122.11	132.18	143.25	8.2182	0.1342	2.5584	4.7471	2.2186
105	131.98	138.62	145.27	5.8259	137.49	140.61	145.23	4.0288	-0.4733	1.9858	5.6164	2.4462

Device Test: 38.12 _EA|SourceCurrent/COMP4/3/3///90.9/634//0///@EA_SOURCE





Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

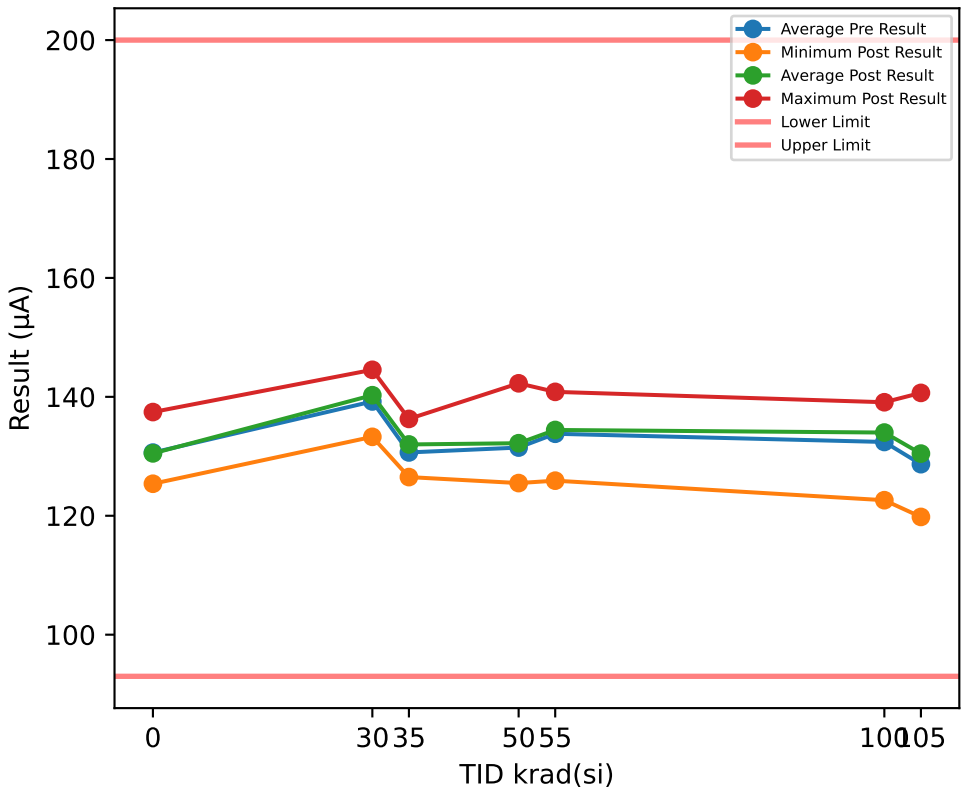
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	138.84	138.54	-0.3048
2	0	CU2	130.58	130.39	-0.1871
3	0	CU3	138.49	138.26	-0.227
11	30	Unbiased-30krad	140.78	141.22	0.4405
12	30	Unbiased-30krad	142.67	142.21	-0.4544
13	30	Unbiased-30krad	132.61	134.56	1.9467
14	30	Unbiased-30krad	127.67	128.59	0.9218
15	30	Unbiased-30krad	131.07	132.62	1.555
16	35	Biased-30krad	132.29	133.34	1.0494
17	35	Biased-30krad	130.72	131.27	0.5579
18	35	Biased-30krad	131.58	131.61	0.0285
19	35	Biased-30krad	141.03	141.12	0.0812
20	35	Biased-30krad	130.59	132.05	1.4618
30	50	Unbiased-50krad	143.11	145.85	2.7441
31	50	Unbiased-50krad	139.71	139.15	-0.5527
32	50	Unbiased-50krad	127.59	129.39	1.796
33	50	Unbiased-50krad	138.04	138.51	0.4699
34	50	Unbiased-50krad	140.85	141.88	1.0313
40	55	Biased-50krad	125.85	127.21	1.3531
41	55	Biased-50krad	138.57	139.01	0.4362
42	55	Biased-50krad	139.95	140.59	0.64
43	55	Biased-50krad	133.94	135.29	1.3459
44	55	Biased-50krad	127.35	128.02	0.6686
45	100	Unbiased-100krad	126.75	131.18	4.4282
46	100	Unbiased-100krad	122.63	124.48	1.8499
47	100	Unbiased-100krad	132.73	133.87	1.1388
48	100	Unbiased-100krad	140.4	141.61	1.2168
49	100	Unbiased-100krad	129.59	133.4	3.8119
50	105	Biased-100krad	134.17	131.66	-2.5134
51	105	Biased-100krad	126.53	128.62	2.0992
52	105	Biased-100krad	133.8	139.8	6.0018
53	105	Biased-100krad	130.65	131.14	0.4888
54	105	Biased-100krad	139.21	141.05	1.834

Test Statistics (µA)

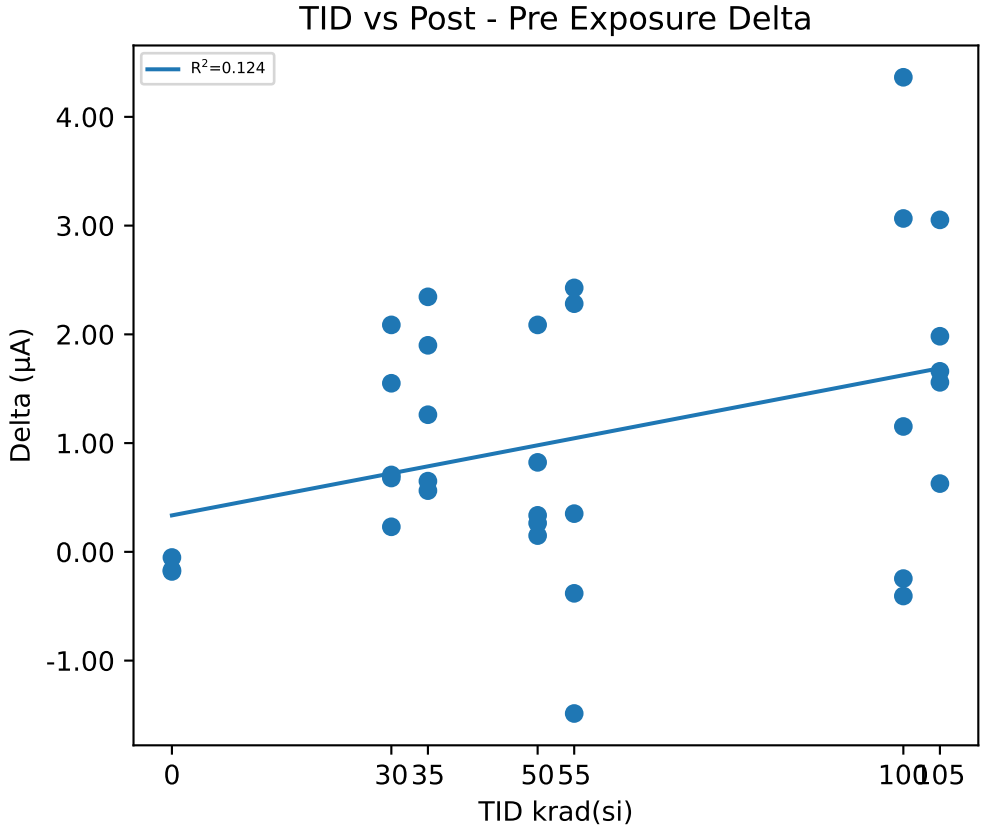
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	130.58	135.97	138.84	4.6704	130.39	135.73	138.54	4.6236	-0.3048	-0.23963	-0.1871	0.059858
30	127.67	134.96	142.67	6.4642	128.59	135.84	142.21	5.7912	-0.4544	0.88192	1.9467	0.94459
35	130.59	133.24	141.03	4.4108	131.27	133.88	141.12	4.1215	0.0285	0.63576	1.4618	0.61964
50	127.59	137.86	143.11	6.0293	129.39	138.96	145.85	6.082	-0.5527	1.0977	2.7441	1.257
55	125.85	133.13	139.95	6.3867	127.21	134.02	140.59	6.1666	0.4362	0.88876	1.3531	0.43004
100	122.63	130.42	140.4	6.7013	124.48	132.91	141.61	6.1419	1.1388	2.4891	4.4282	1.5298
105	126.53	132.87	139.21	4.6898	128.62	134.45	141.05	5.5873	-2.5134	1.5821	6.0018	3.0754

Device Test: 38.13 _EA|SinkCurrent/COMP1/3/3///90.9/634//0///@EA_SINK

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

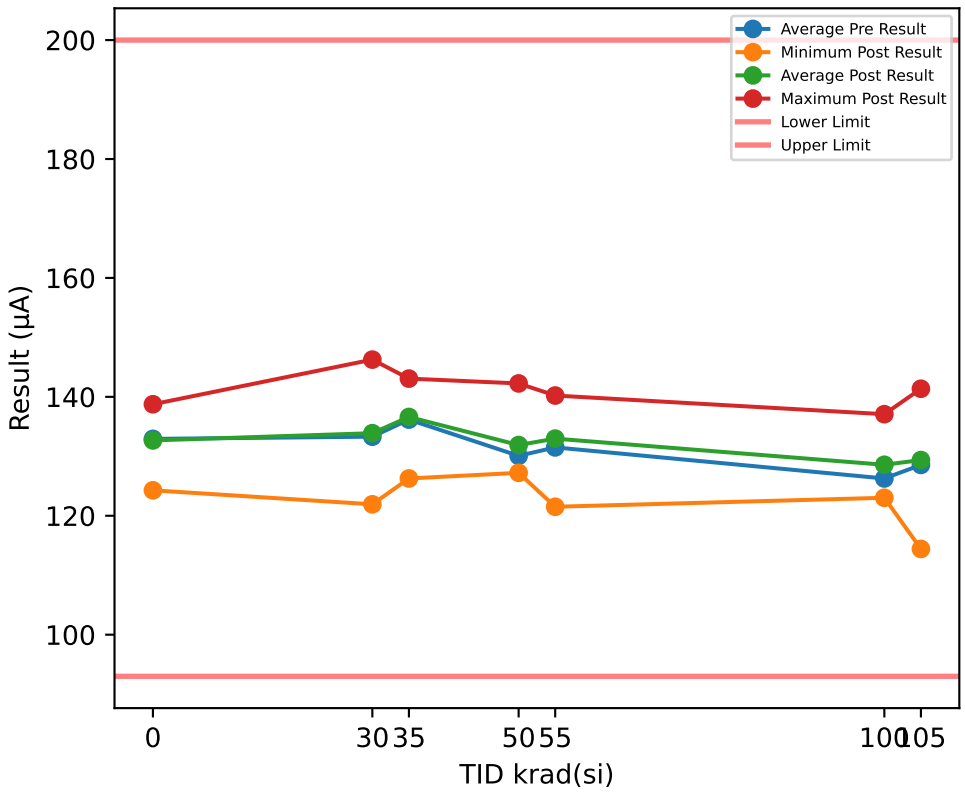
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	137.62	137.44	-0.1802
2	0	CU2	128.82	128.65	-0.1683
3	0	CU3	125.44	125.38	-0.0518
11	30	Unbiased-30krad	131.19	133.27	2.087
12	30	Unbiased-30krad	142.67	143.35	0.679
13	30	Unbiased-30krad	143	144.55	1.5503
14	30	Unbiased-30krad	137.14	137.37	0.2304
15	30	Unbiased-30krad	142.13	142.84	0.7072
16	35	Biased-30krad	124.61	126.51	1.8992
17	35	Biased-30krad	133.94	136.29	2.3451
18	35	Biased-30krad	131.04	132.3	1.261
19	35	Biased-30krad	133.59	134.24	0.6503
20	35	Biased-30krad	130.07	130.64	0.5629
30	50	Unbiased-50krad	128.01	128.28	0.2644
31	50	Unbiased-50krad	133	133.82	0.8229
32	50	Unbiased-50krad	130.8	131.13	0.3358
33	50	Unbiased-50krad	125.35	125.5	0.1494
34	50	Unbiased-50krad	140.19	142.28	2.0869
40	55	Biased-50krad	141.22	140.84	-0.3815
41	55	Biased-50krad	125.55	125.9	0.3514
42	55	Biased-50krad	142.08	140.6	-1.4865
43	55	Biased-50krad	131.83	134.26	2.4273
44	55	Biased-50krad	128.27	130.55	2.282
45	100	Unbiased-100krad	134.73	139.09	4.3639
46	100	Unbiased-100krad	122.86	122.62	-0.2457
47	100	Unbiased-100krad	133.28	136.34	3.0656
48	100	Unbiased-100krad	135.69	136.84	1.1529
49	100	Unbiased-100krad	135.49	135.09	-0.4061
50	105	Biased-100krad	135.53	137.19	1.6602
51	105	Biased-100krad	124.49	127.55	3.0528
52	105	Biased-100krad	125.08	127.06	1.9826
53	105	Biased-100krad	119.18	119.8	0.6277
54	105	Biased-100krad	139.11	140.66	1.5587

Test Statistics (µA)

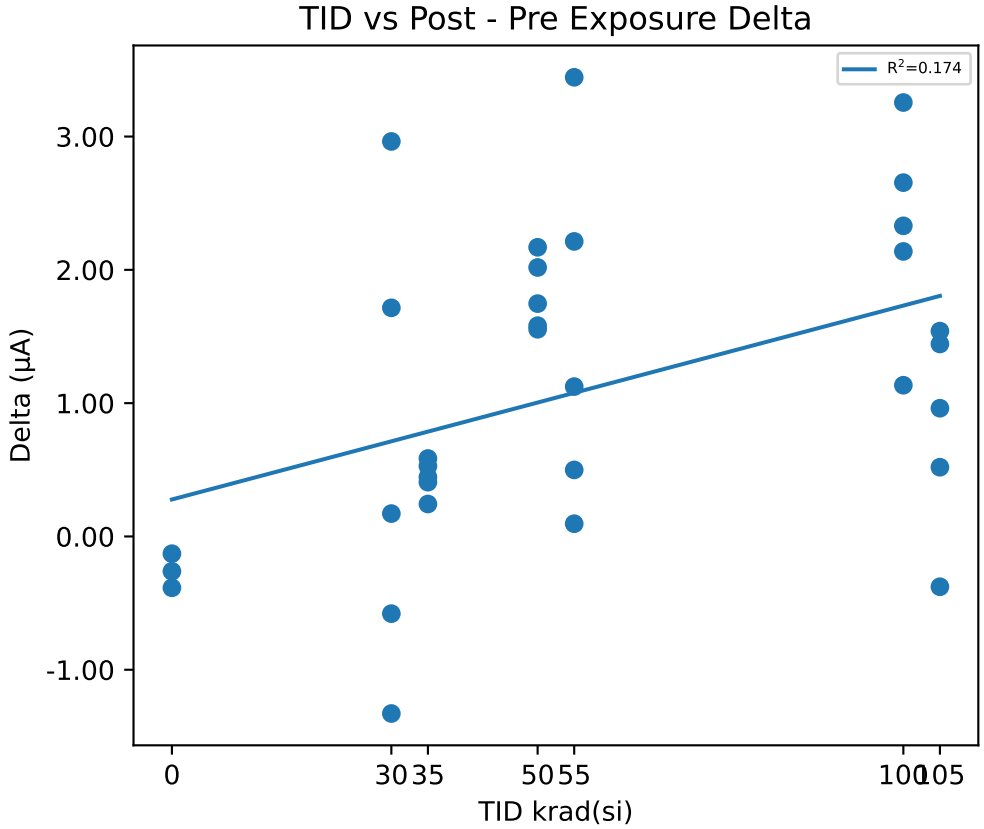
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	125.44	130.63	137.62	6.2898	125.38	130.49	137.44	6.2353	-0.1802	-0.13343	-0.0518	0.070946
30	131.19	139.22	143	5.0878	133.27	140.28	144.55	4.7899	0.2304	1.0508	2.087	0.75043
35	124.61	130.65	133.94	3.7584	126.51	131.99	136.29	3.7264	0.5629	1.3437	2.3451	0.776
50	125.35	131.47	140.19	5.6621	125.5	132.2	142.28	6.4342	0.1494	0.73188	2.0869	0.79985
55	125.55	133.79	142.08	7.5185	125.9	134.43	140.84	6.4582	-1.4865	0.63854	2.4273	1.6985
100	122.86	132.41	135.69	5.4206	122.62	134	139.09	6.524	-0.4061	1.5861	4.3639	2.0867
105	119.18	128.68	139.11	8.3126	119.8	130.45	140.66	8.4109	0.6277	1.7764	3.0528	0.87352

Device Test: 38.14 _EA|SinkCurrent/COMP2/3/3///90.9/634//0///@EA_SINK

TID vs Result Stats



TID vs Post - Pre Exposure Delta



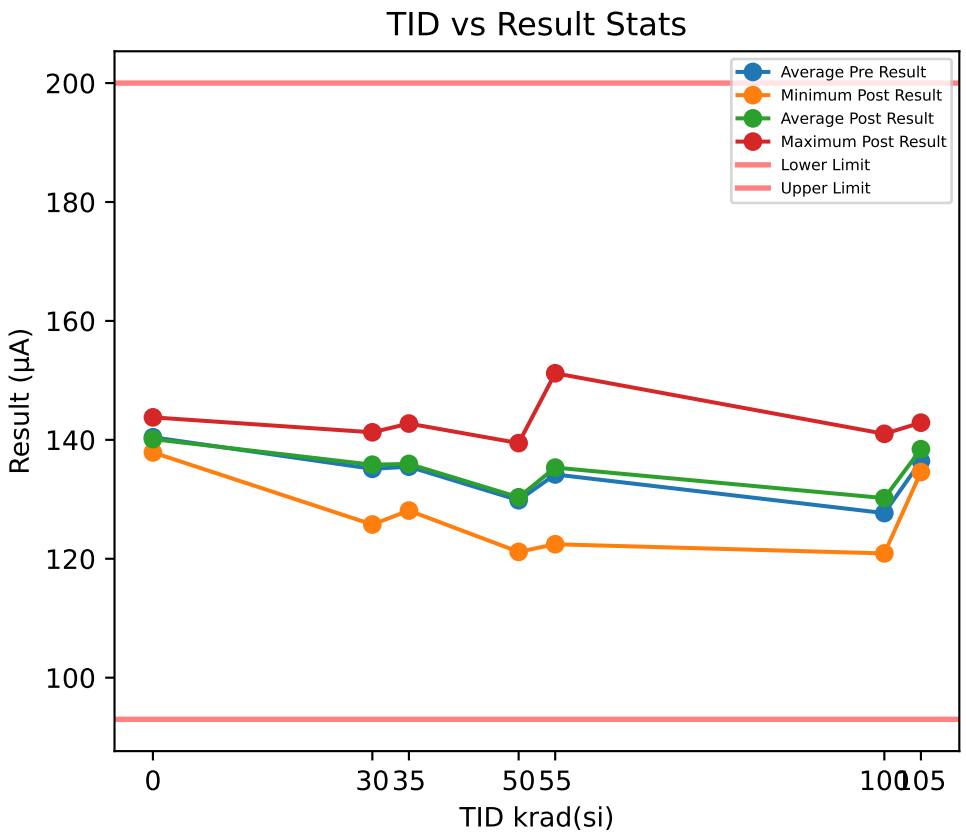
Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

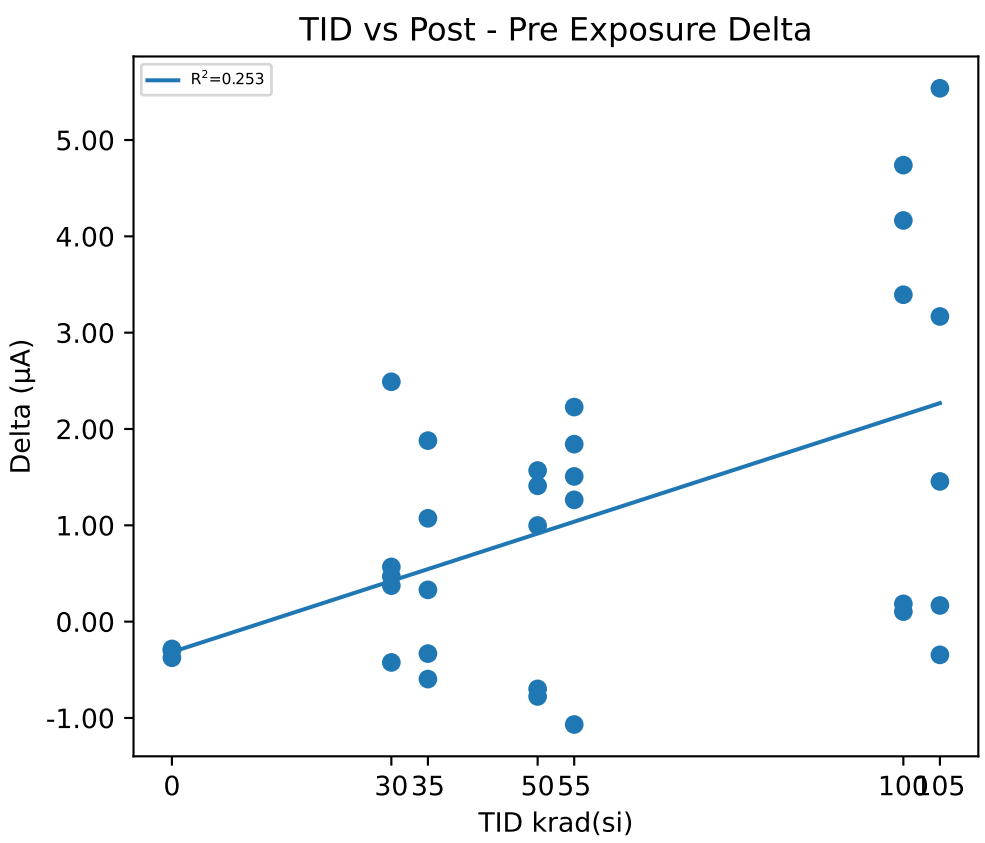
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	139.14	138.75	-0.3852
2	0	CU2	124.41	124.28	-0.1292
3	0	CU3	135.25	134.98	-0.2614
11	30	Unbiased-30krad	134.43	133.85	-0.579
12	30	Unbiased-30krad	138.78	137.45	-1.3282
13	30	Unbiased-30krad	143.3	146.26	2.9632
14	30	Unbiased-30krad	120.21	121.93	1.7151
15	30	Unbiased-30krad	129.78	129.96	0.1716
16	35	Biased-30krad	134.62	135.21	0.5848
17	35	Biased-30krad	141.79	142.32	0.5281
18	35	Biased-30krad	135.77	136.21	0.4459
19	35	Biased-30krad	142.66	143.07	0.4071
20	35	Biased-30krad	126.03	126.27	0.2434
30	50	Unbiased-50krad	125.48	127.22	1.7467
31	50	Unbiased-50krad	127.05	128.63	1.5812
32	50	Unbiased-50krad	126.29	128.46	2.1693
33	50	Unbiased-50krad	131.34	132.9	1.5542
34	50	Unbiased-50krad	140.24	142.26	2.0178
40	55	Biased-50krad	128.8	131.01	2.2133
41	55	Biased-50krad	139.34	139.44	0.0956
42	55	Biased-50krad	139.1	140.22	1.1243
43	55	Biased-50krad	129.24	132.68	3.4445
44	55	Biased-50krad	121.02	121.52	0.4992
45	100	Unbiased-100krad	121.89	123.02	1.1345
46	100	Unbiased-100krad	127.38	129.52	2.1382
47	100	Unbiased-100krad	127.63	129.96	2.3302
48	100	Unbiased-100krad	134.43	137.08	2.6542
49	100	Unbiased-100krad	120.04	123.29	3.2552
50	105	Biased-100krad	127.65	129.1	1.4438
51	105	Biased-100krad	112.88	114.42	1.5405
52	105	Biased-100krad	131	130.63	-0.3773
53	105	Biased-100krad	130.38	131.34	0.9619
54	105	Biased-100krad	140.84	141.36	0.5195

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	124.41	132.93	139.14	7.631	124.28	132.67	138.75	7.5069	-0.3852	-0.2586	-0.1292	0.12802
30	120.21	133.3	143.3	8.8741	121.93	133.89	146.26	9.0054	-1.3282	0.58854	2.9632	1.7406
35	126.03	136.17	142.66	6.6925	126.27	136.62	143.07	6.7698	0.2434	0.44186	0.5848	0.13084
50	125.48	130.08	140.24	6.1143	127.22	131.89	142.26	6.1777	1.5542	1.8138	2.1693	0.27111
55	121.02	131.5	139.34	7.7704	121.52	132.97	140.22	7.5748	0.0956	1.4754	3.4445	1.3603
100	120.04	126.27	134.43	5.6496	123.02	128.58	137.08	5.7858	1.1345	2.3025	3.2552	0.77835
105	112.88	128.55	140.84	10.084	114.42	129.37	141.36	9.6536	-0.3773	0.81768	1.5405	0.78297

Device Test: 38.15 _EA|SinkCurrent/COMP3/3/3///90.9/634//0///@EA_SINK





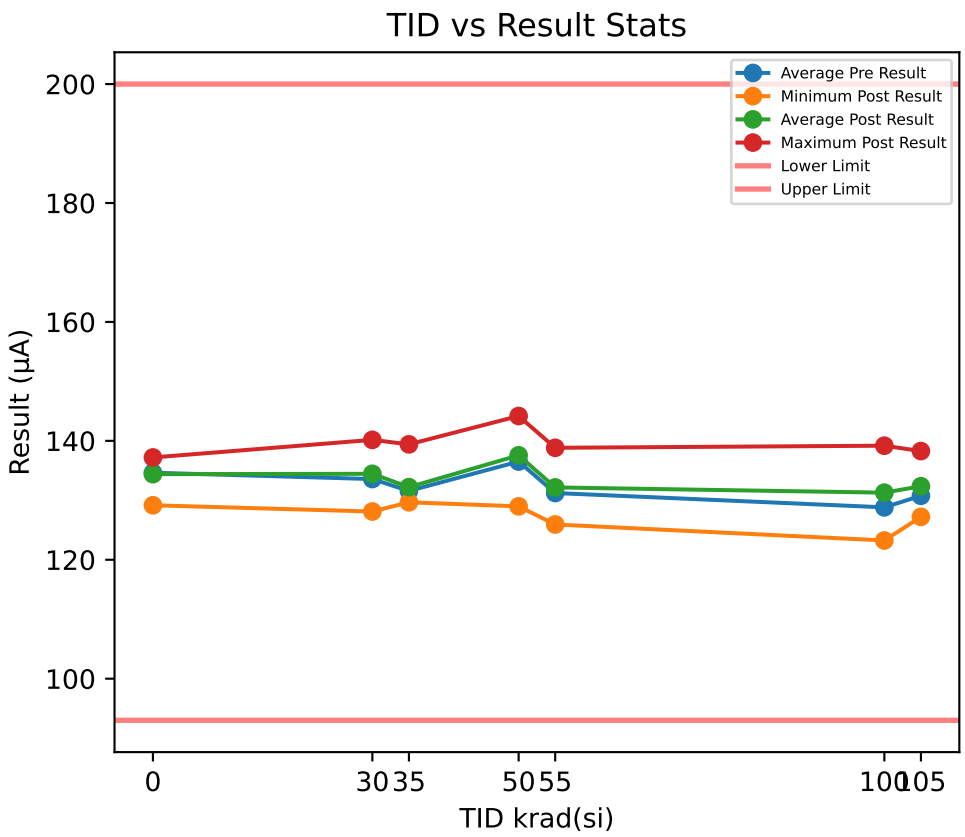
Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

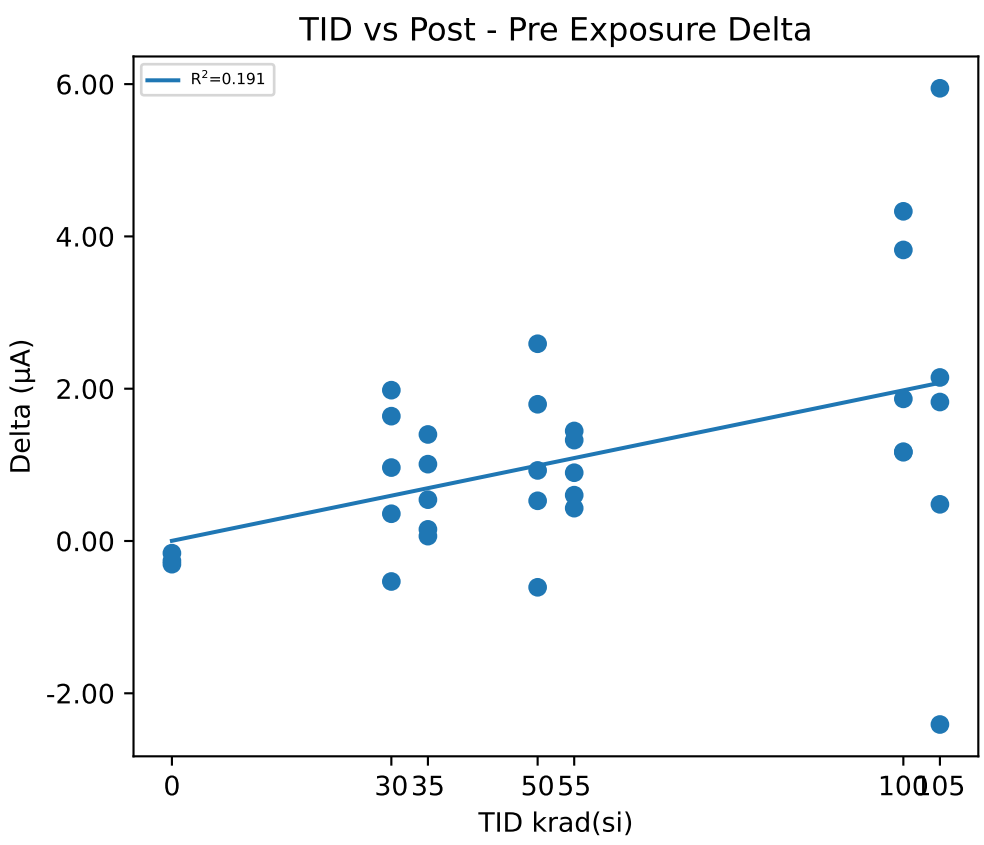
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	144.16	143.78	-0.3751
2	0	CU2	138.17	137.89	-0.2834
3	0	CU3	139	138.7	-0.3
11	30	Unbiased-30krad	139.36	139.73	0.3734
12	30	Unbiased-30krad	134.89	135.36	0.47
13	30	Unbiased-30krad	136.41	136.97	0.568
14	30	Unbiased-30krad	123.27	125.76	2.4901
15	30	Unbiased-30krad	141.69	141.27	-0.4237
16	35	Biased-30krad	129.74	129.41	-0.3319
17	35	Biased-30krad	136.26	138.14	1.8791
18	35	Biased-30krad	141.67	142.74	1.0727
19	35	Biased-30krad	141.05	141.38	0.3298
20	35	Biased-30krad	128.7	128.11	-0.5964
30	50	Unbiased-50krad	119.59	121.16	1.5686
31	50	Unbiased-50krad	130.42	131.83	1.4099
32	50	Unbiased-50krad	128.83	128.06	-0.7766
33	50	Unbiased-50krad	130.21	131.21	0.9981
34	50	Unbiased-50krad	140.15	139.45	-0.698
40	55	Biased-50krad	142.74	144.58	1.8423
41	55	Biased-50krad	128.46	127.4	-1.068
42	55	Biased-50krad	148.97	151.2	2.2275
43	55	Biased-50krad	121.18	122.44	1.2642
44	55	Biased-50krad	129.54	131.05	1.5075
45	100	Unbiased-100krad	124.8	124.91	0.104
46	100	Unbiased-100krad	117.51	120.9	3.3937
47	100	Unbiased-100krad	130.31	130.5	0.1847
48	100	Unbiased-100krad	136.27	141.01	4.7391
49	100	Unbiased-100krad	129.52	133.68	4.165
50	105	Biased-100krad	142.24	141.9	-0.3449
51	105	Biased-100krad	132.75	135.91	3.1681
52	105	Biased-100krad	136.7	136.87	0.1679
53	105	Biased-100krad	129.04	134.58	5.537
54	105	Biased-100krad	141.43	142.89	1.4556

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	138.17	140.44	144.16	3.245	137.89	140.12	143.78	3.1962	-0.3751	-0.3195	-0.2834	0.048861
30	123.27	135.12	141.69	7.1289	125.76	135.82	141.27	6.0773	-0.4237	0.69556	2.4901	1.0775
35	128.7	135.48	141.67	6.0978	128.11	135.95	142.74	6.7939	-0.5964	0.47066	1.8791	1.0184
50	119.59	129.84	140.15	7.2949	121.16	130.34	139.45	6.6244	-0.7766	0.5004	1.5686	1.1492
55	121.18	134.18	148.97	11.35	122.44	135.33	151.2	12.092	-1.068	1.1547	2.2275	1.2943
100	117.51	127.68	136.27	6.9987	120.9	130.2	141.01	7.8042	0.104	2.5173	4.7391	2.2184
105	129.04	136.43	142.24	5.6356	134.58	138.43	142.89	3.7246	-0.3449	1.9967	5.537	2.3993

Device Test: 38.16 _EA|SinkCurrent/COMP4/3/3///90.9/634//0///@EA_SINK





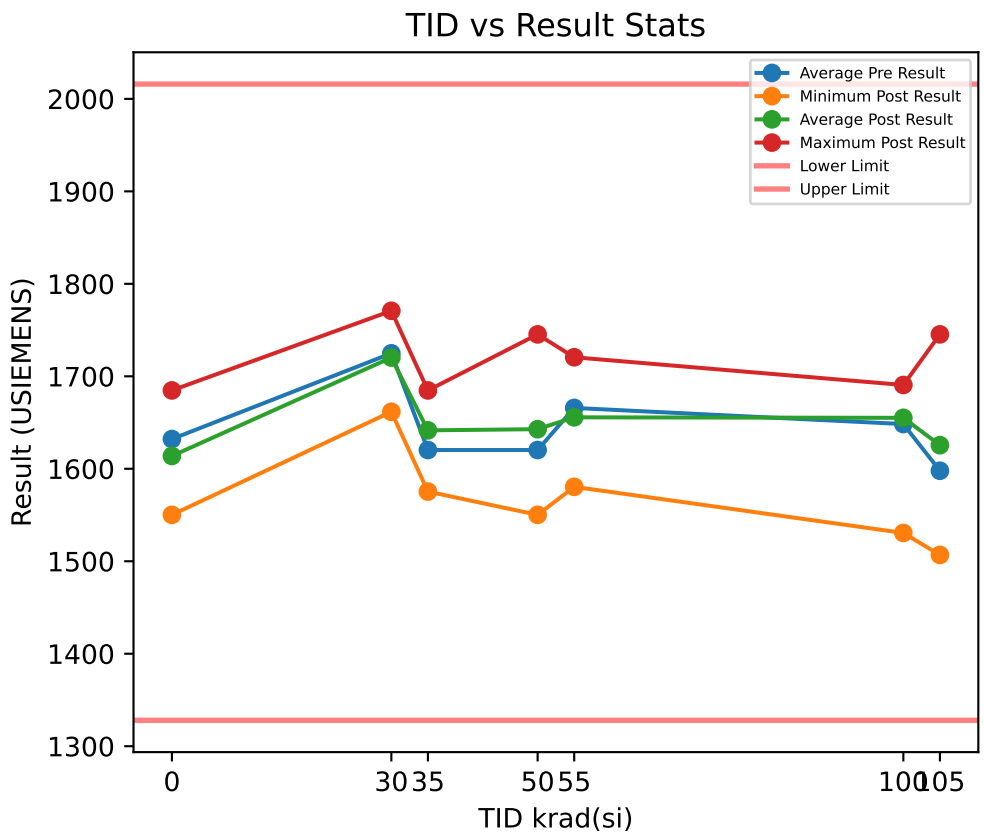
Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

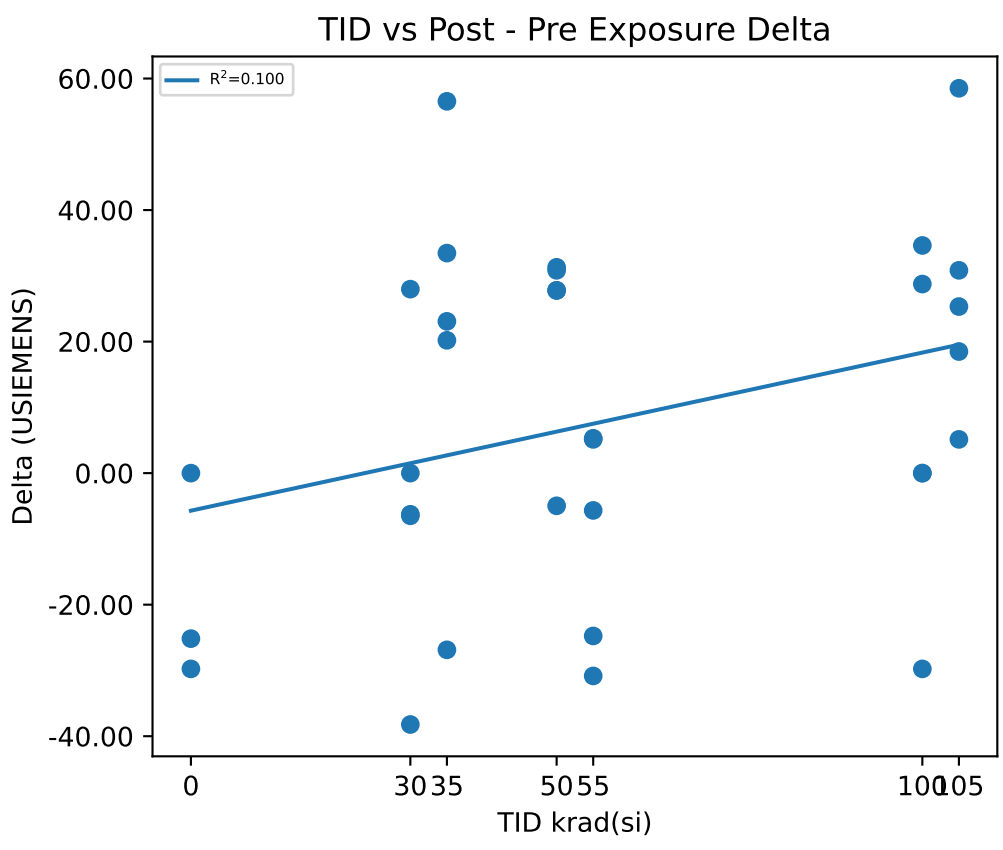
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	137.51	137.21	-0.3046
2	0	CU2	129.32	129.16	-0.1596
3	0	CU3	137.09	136.83	-0.2609
11	30	Unbiased-30krad	139.81	140.17	0.3579
12	30	Unbiased-30krad	140.47	139.94	-0.5317
13	30	Unbiased-30krad	130.51	132.49	1.9807
14	30	Unbiased-30krad	127.15	128.12	0.9643
15	30	Unbiased-30krad	129.93	131.57	1.6394
16	35	Biased-30krad	131.04	132.05	1.0091
17	35	Biased-30krad	129.12	129.67	0.5428
18	35	Biased-30krad	129.63	129.69	0.0638
19	35	Biased-30krad	139.26	139.41	0.1529
20	35	Biased-30krad	128.83	130.23	1.3992
30	50	Unbiased-50krad	141.59	144.18	2.5903
31	50	Unbiased-50krad	137.81	137.2	-0.6081
32	50	Unbiased-50krad	127.19	128.98	1.7956
33	50	Unbiased-50krad	136.98	137.5	0.528
34	50	Unbiased-50krad	139.03	139.96	0.9268
40	55	Biased-50krad	124.93	126.37	1.445
41	55	Biased-50krad	135.7	136.13	0.4312
42	55	Biased-50krad	138.23	138.83	0.6019
43	55	Biased-50krad	132.22	133.55	1.3248
44	55	Biased-50krad	125.04	125.94	0.8967
45	100	Unbiased-100krad	124.65	128.98	4.3294
46	100	Unbiased-100krad	121.38	123.25	1.8664
47	100	Unbiased-100krad	132.09	133.26	1.173
48	100	Unbiased-100krad	138.02	139.18	1.1653
49	100	Unbiased-100krad	127.95	131.77	3.8224
50	105	Biased-100krad	132.28	129.87	-2.4099
51	105	Biased-100krad	125.07	127.22	2.1477
52	105	Biased-100krad	132.08	138.03	5.9452
53	105	Biased-100krad	127.94	128.42	0.4815
54	105	Biased-100krad	136.45	138.28	1.8251

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	129.32	134.64	137.51	4.6097	129.16	134.4	137.21	4.5377	-0.3046	-0.2417	-0.1596	0.074382
30	127.15	133.57	140.47	6.1305	128.12	134.46	140.17	5.3631	-0.5317	0.88212	1.9807	1.0076
35	128.83	131.58	139.26	4.376	129.67	132.21	139.41	4.1404	0.0638	0.63356	1.3992	0.56814
50	127.19	136.52	141.59	5.4988	128.98	137.56	144.18	5.5505	-0.6081	1.0465	2.5903	1.2212
55	124.93	131.22	138.23	6.0834	125.94	132.16	138.83	5.7978	0.4312	0.93992	1.445	0.44107
100	121.38	128.82	138.02	6.4952	123.25	131.29	139.18	5.8402	1.1653	2.4713	4.3294	1.5029
105	125.07	130.77	136.45	4.3828	127.22	132.36	138.28	5.3697	-2.4099	1.5979	5.9452	3.0233

Device Test: 38.17 _EA|Transconductance/VSNS1/3/3///90.9/634//0///@EA_GM_25C





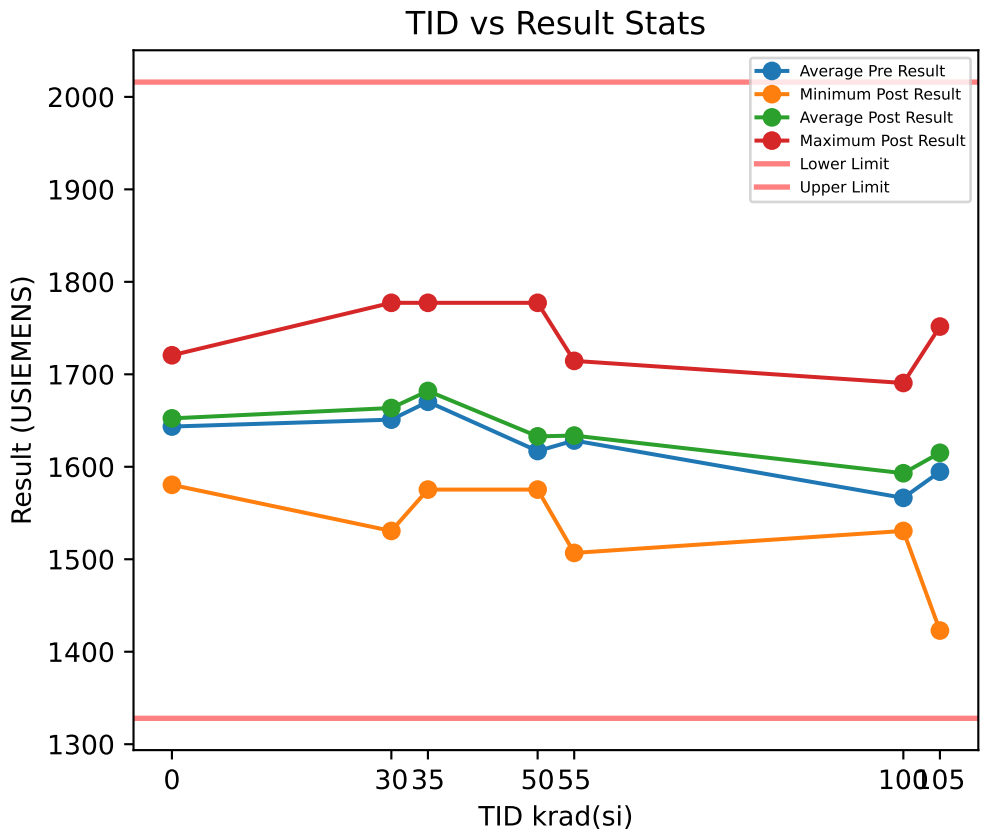
Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

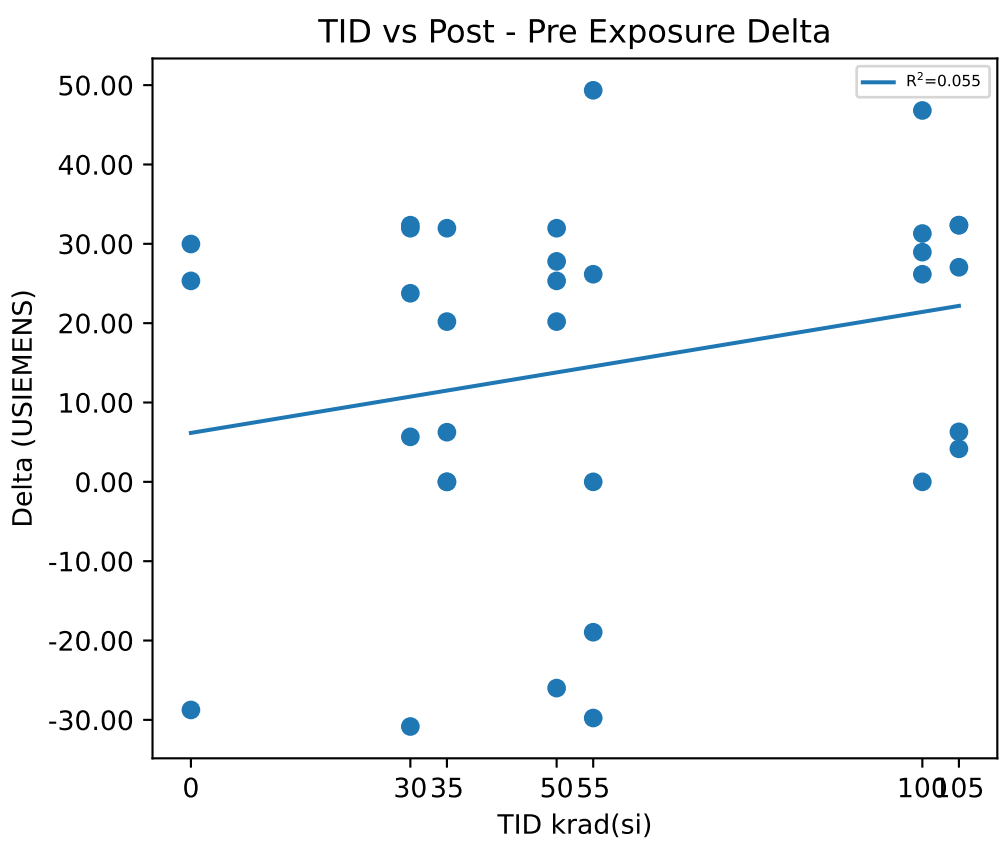
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1714.5	1684.7	-29.766
2	0	CU2	1606.6	1606.6	0
3	0	CU3	1575.3	1550.2	-25.165
11	30	Unbiased-30krad	1633.7	1661.7	27.974
12	30	Unbiased-30krad	1745.3	1739.1	-6.2557
13	30	Unbiased-30krad	1777.3	1770.8	-6.4865
14	30	Unbiased-30krad	1690.6	1690.6	0
15	30	Unbiased-30krad	1777.3	1739.1	-38.222
16	35	Biased-30krad	1555.1	1575.3	20.197
17	35	Biased-30krad	1661.7	1684.7	23.079
18	35	Biased-30krad	1628.2	1661.7	33.456
19	35	Biased-30krad	1628.2	1684.7	56.535
20	35	Biased-30krad	1628.2	1601.3	-26.868
30	50	Unbiased-50krad	1575.3	1606.6	31.298
31	50	Unbiased-50krad	1628.2	1656	27.785
32	50	Unbiased-50krad	1628.2	1656	27.785
33	50	Unbiased-50krad	1555.1	1550.2	-4.9685
34	50	Unbiased-50krad	1714.5	1745.3	30.836
40	55	Biased-50krad	1745.3	1714.5	-30.836
41	55	Biased-50krad	1575.3	1580.5	5.1314
42	55	Biased-50krad	1745.3	1720.6	-24.757
43	55	Biased-50krad	1661.7	1656	-5.6712
44	55	Biased-50krad	1601.3	1606.6	5.3024
45	100	Unbiased-100krad	1656	1690.6	34.62
46	100	Unbiased-100krad	1530.6	1530.6	0
47	100	Unbiased-100krad	1656	1684.7	28.75
48	100	Unbiased-100krad	1714.5	1684.7	-29.766
49	100	Unbiased-100krad	1684.7	1684.7	0
50	105	Biased-100krad	1656	1714.5	58.515
51	105	Biased-100krad	1575.3	1580.5	5.1314
52	105	Biased-100krad	1555.1	1580.5	25.328
53	105	Biased-100krad	1488.4	1506.8	18.489
54	105	Biased-100krad	1714.5	1745.3	30.836

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1632.2	1714.5	73.008	1550.2	1613.9	1684.7	67.571	-29.766	-18.31	0	16.023
30	1633.7	1724.9	1777.3	62.062	1661.7	1720.3	1770.8	43.527	-38.222	-4.598	27.974	23.553
35	1555.1	1620.3	1661.7	39.19	1575.3	1641.6	1684.7	50.339	-26.868	21.28	56.535	30.471
50	1555.1	1620.3	1714.5	61.778	1550.2	1642.8	1745.3	72.024	-4.9685	22.547	31.298	15.47
55	1575.3	1665.8	1745.3	79.072	1580.5	1655.6	1720.6	62.718	-30.836	-10.166	5.3024	16.835
100	1530.6	1648.4	1714.5	70.141	1530.6	1655.1	1690.6	69.629	-29.766	6.7208	34.62	25.91
105	1488.4	1597.9	1714.5	88.469	1506.8	1625.5	1745.3	100.52	5.1314	27.66	58.515	19.744

Device Test: 38.18 _EA|Transconductance/VSNS2/3/3///90.9/634//0///@EA_GM_25C





Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

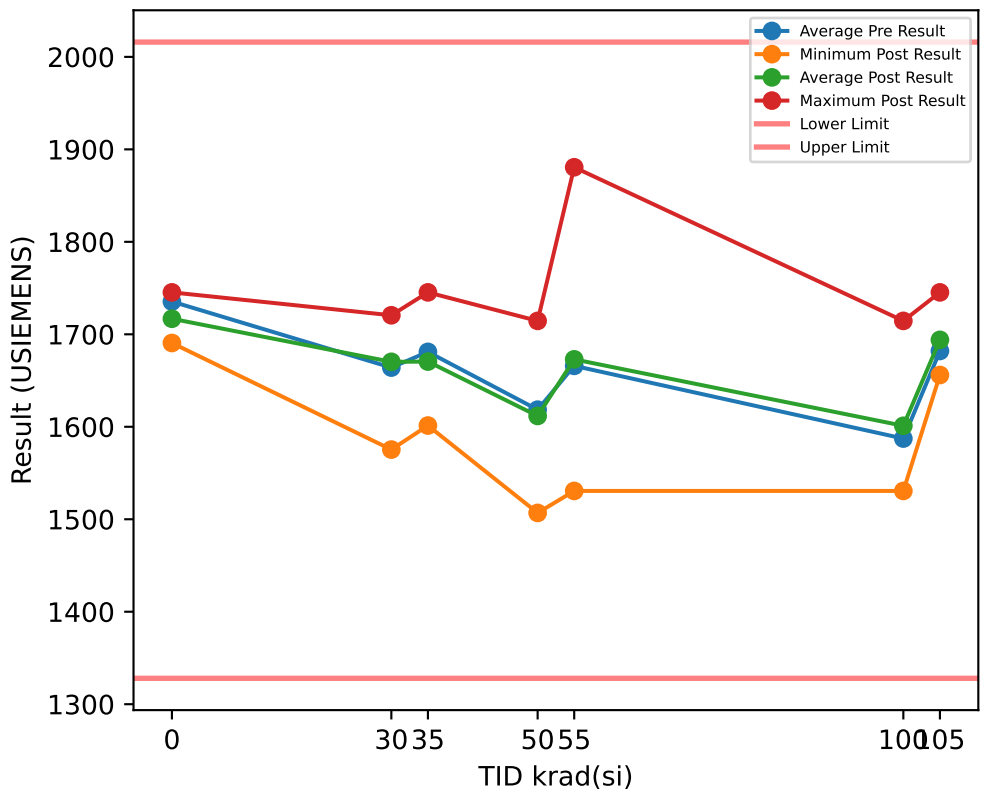
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1690.6	1720.6	29.975
2	0	CU2	1555.1	1580.5	25.328
3	0	CU3	1684.7	1656	-28.75
11	30	Unbiased-30krad	1656	1661.7	5.6712
12	30	Unbiased-30krad	1745.3	1714.5	-30.836
13	30	Unbiased-30krad	1745.3	1777.3	31.966
14	30	Unbiased-30krad	1506.8	1530.6	23.767
15	30	Unbiased-30krad	1601.3	1633.7	32.35
16	35	Biased-30krad	1656	1656	0
17	35	Biased-30krad	1739.1	1745.3	6.2557
18	35	Biased-30krad	1656	1656	0
19	35	Biased-30krad	1745.3	1777.3	31.966
20	35	Biased-30krad	1555.1	1575.3	20.197
30	50	Unbiased-50krad	1555.1	1580.5	25.328
31	50	Unbiased-50krad	1555.1	1575.3	20.197
32	50	Unbiased-50krad	1601.3	1575.3	-25.996
33	50	Unbiased-50krad	1628.2	1656	27.785
34	50	Unbiased-50krad	1745.3	1777.3	31.966
40	55	Biased-50krad	1580.5	1606.6	26.167
41	55	Biased-50krad	1714.5	1684.7	-29.766
42	55	Biased-50krad	1714.5	1714.5	0
43	55	Biased-50krad	1606.6	1656	49.351
44	55	Biased-50krad	1525.8	1506.8	-18.954
45	100	Unbiased-100krad	1530.6	1530.6	0
46	100	Unbiased-100krad	1580.5	1606.6	26.167
47	100	Unbiased-100krad	1575.3	1606.6	31.298
48	100	Unbiased-100krad	1661.7	1690.6	28.949
49	100	Unbiased-100krad	1483.8	1530.6	46.808
50	105	Biased-100krad	1601.3	1633.7	32.35
51	105	Biased-100krad	1418.7	1422.9	4.1605
52	105	Biased-100krad	1606.6	1633.7	27.048
53	105	Biased-100krad	1601.3	1633.7	32.35
54	105	Biased-100krad	1745.3	1751.6	6.3009

Test Statistics (USIEMENS)

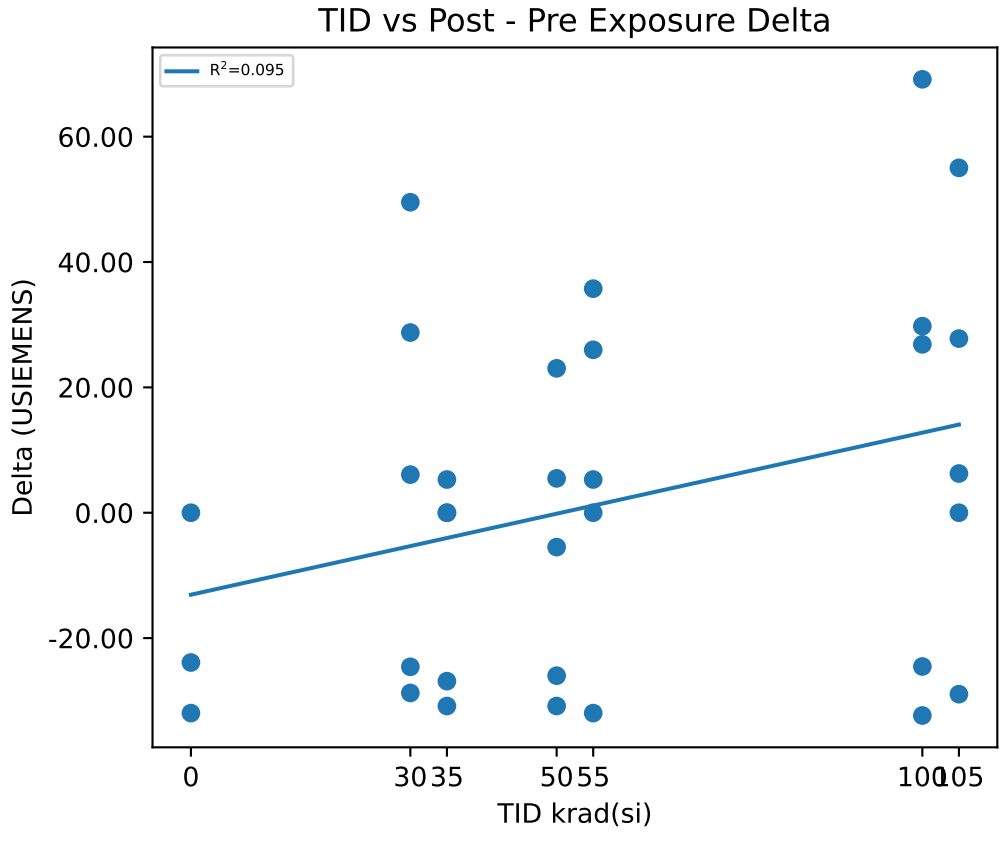
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1555.1	1643.5	1690.6	76.573	1580.5	1652.3	1720.6	70.127	-28.75	8.8512	29.975	32.646
30	1506.8	1651	1745.3	101.33	1530.6	1663.6	1777.3	92.337	-30.836	12.584	32.35	26.573
35	1555.1	1670.3	1745.3	77.513	1575.3	1682	1777.3	80.351	0	11.684	31.966	14.021
50	1555.1	1617	1745.3	78.254	1575.3	1632.9	1777.3	87.695	-25.996	15.856	31.966	23.78
55	1525.8	1628.4	1714.5	83.853	1506.8	1633.7	1714.5	81.325	-29.766	5.3595	49.351	32.488
100	1483.8	1566.4	1661.7	66.058	1530.6	1593	1690.6	66.49	0	26.644	46.808	16.909
105	1418.7	1594.7	1745.3	116.07	1422.9	1615.1	1751.6	118.98	4.1605	20.442	32.35	14.074

Device Test: 38.19 _EA|Transconductance/VSNS3/3/3///90.9/634//0///@EA_GM_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



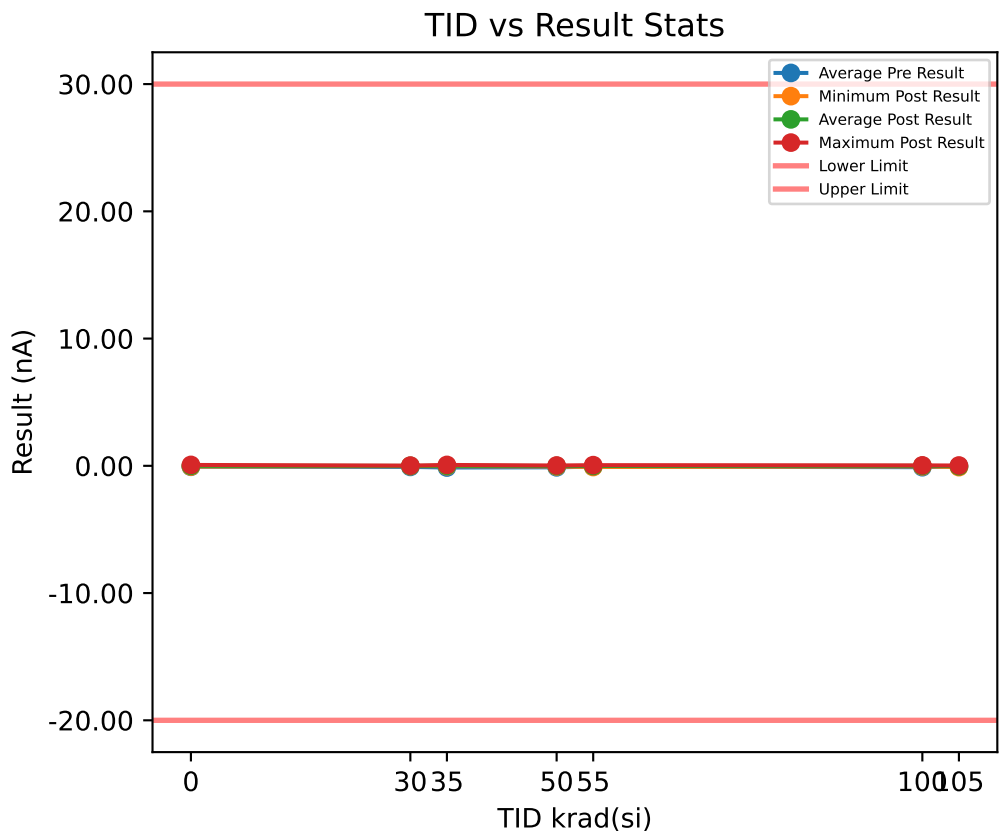
Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

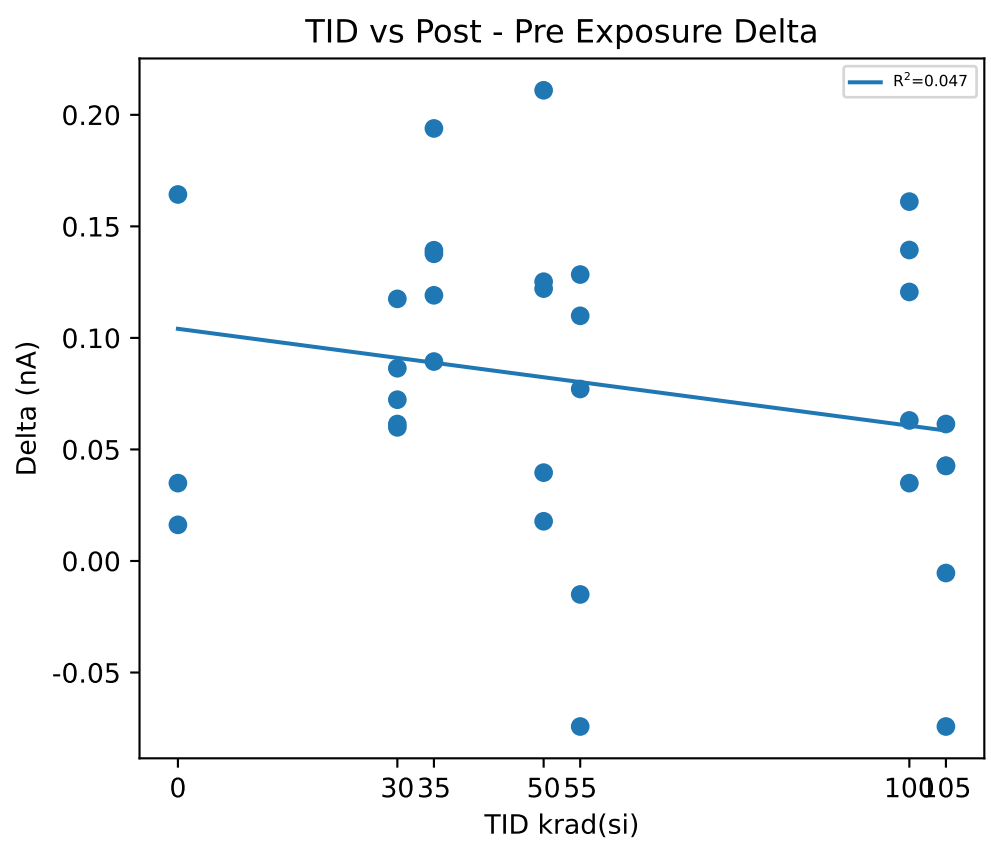
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1777.3	1745.3	-31.966
2	0	CU2	1714.5	1690.6	-23.895
3	0	CU3	1714.5	1714.5	0
11	30	Unbiased-30krad	1714.5	1720.6	6.0798
12	30	Unbiased-30krad	1684.7	1656	-28.75
13	30	Unbiased-30krad	1656	1684.7	28.75
14	30	Unbiased-30krad	1525.8	1575.3	49.539
15	30	Unbiased-30krad	1739.1	1714.5	-24.581
16	35	Biased-30krad	1628.2	1601.3	-26.868
17	35	Biased-30krad	1684.7	1684.7	0
18	35	Biased-30krad	1745.3	1745.3	0
19	35	Biased-30krad	1745.3	1714.5	-30.836
20	35	Biased-30krad	1601.3	1606.6	5.3024
30	50	Unbiased-50krad	1483.8	1506.8	23.04
31	50	Unbiased-50krad	1628.2	1633.7	5.4821
32	50	Unbiased-50krad	1601.3	1575.3	-25.996
33	50	Unbiased-50krad	1633.7	1628.2	-5.4821
34	50	Unbiased-50krad	1745.3	1714.5	-30.836
40	55	Biased-50krad	1777.3	1745.3	-31.966
41	55	Biased-50krad	1575.3	1601.3	25.996
42	55	Biased-50krad	1844.9	1880.6	35.754
43	55	Biased-50krad	1530.6	1530.6	0
44	55	Biased-50krad	1601.3	1606.6	5.3024
45	100	Unbiased-100krad	1555.1	1530.6	-24.529
46	100	Unbiased-100krad	1461.5	1530.6	69.154
47	100	Unbiased-100krad	1633.7	1601.3	-32.35
48	100	Unbiased-100krad	1684.7	1714.5	29.766
49	100	Unbiased-100krad	1601.3	1628.2	26.868
50	105	Biased-100krad	1739.1	1745.3	6.2557
51	105	Biased-100krad	1628.2	1656	27.785
52	105	Biased-100krad	1690.6	1661.7	-28.949
53	105	Biased-100krad	1606.6	1661.7	55.022
54	105	Biased-100krad	1745.3	1745.3	0

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1714.5	1735.4	1777.3	36.259	1690.6	1716.8	1745.3	27.439	-31.966	-18.62	0	16.623
30	1525.8	1664	1739.1	83.339	1575.3	1670.2	1720.6	58.977	-28.75	6.2076	49.539	33.748
35	1601.3	1681	1745.3	66.006	1601.3	1670.5	1745.3	64.425	-30.836	-10.48	5.3024	16.968
50	1483.8	1618.5	1745.3	93.341	1506.8	1611.7	1714.5	76.878	-30.836	-6.7583	23.04	22.301
55	1530.6	1665.9	1844.9	137.04	1530.6	1672.9	1880.6	139.79	-31.966	7.0171	35.754	26.258
100	1461.5	1587.3	1684.7	84.724	1530.6	1601.1	1714.5	76.7	-32.35	13.782	69.154	42.097
105	1606.6	1682	1745.3	63.084	1656	1694	1745.3	46.926	-28.949	12.023	55.022	31.44

Device Test: 38.2 _EA|Leakage/VSNS2/3/3///90.9/634//0///@IVSNS_LKG





Test Results (Lower Limit = -20.0, Upper Limit = 30.0 (nA))

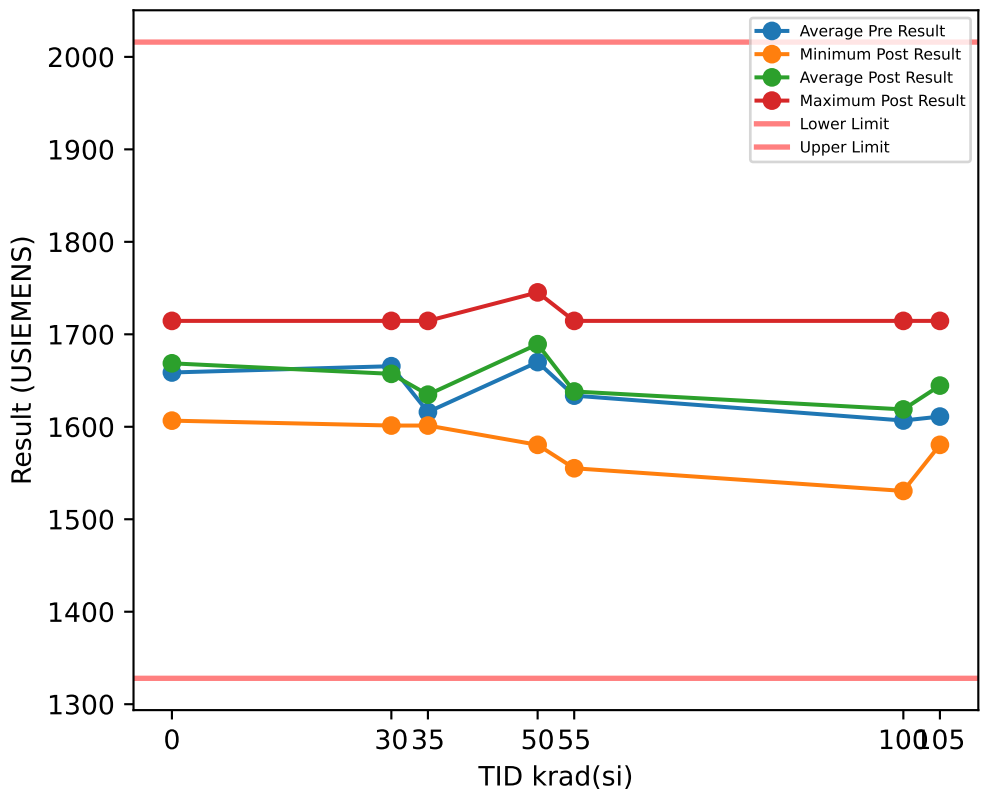
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.0952	-0.0603	0.0349
2	0	CU2	-0.0391	-0.0229	0.0162
3	0	CU3	-0.0936	0.0707	0.1643
11	30	Unbiased-30krad	-0.1326	-0.0151	0.1175
12	30	Unbiased-30krad	-0.0672	-0.0073	0.0599
13	30	Unbiased-30krad	-0.0687	0.0177	0.0864
14	30	Unbiased-30krad	-0.0859	-0.0245	0.0614
15	30	Unbiased-30krad	-0.0718	0.0005	0.0723
16	35	Biased-30krad	-0.1139	-0.0245	0.0894
17	35	Biased-30krad	-0.1668	-0.0291	0.1377
18	35	Biased-30krad	-0.1357	0.0036	0.1393
19	35	Biased-30krad	-0.1232	0.0707	0.1939
20	35	Biased-30krad	-0.1326	-0.0135	0.1191
30	50	Unbiased-50krad	-0.0547	-0.0151	0.0396
31	50	Unbiased-50krad	-0.184	0.027	0.211
32	50	Unbiased-50krad	-0.0703	-0.0525	0.0178
33	50	Unbiased-50krad	-0.1263	-0.0042	0.1221
34	50	Unbiased-50krad	-0.1559	-0.0307	0.1252
40	55	Biased-50krad	-0.1092	0.0192	0.1284
41	55	Biased-50krad	-0.0563	0.0536	0.1099
42	55	Biased-50krad	-0.0205	-0.0947	-0.0742
43	55	Biased-50krad	-0.0781	-0.001	0.0771
44	55	Biased-50krad	-0.0547	-0.0697	-0.015
45	100	Unbiased-100krad	-0.1372	0.0239	0.1611
46	100	Unbiased-100krad	-0.0781	-0.0432	0.0349
47	100	Unbiased-100krad	-0.1513	-0.0307	0.1206
48	100	Unbiased-100krad	-0.0781	-0.0151	0.063
49	100	Unbiased-100krad	-0.103	0.0364	0.1394
50	105	Biased-100krad	-0.1139	-0.0713	0.0426
51	105	Biased-100krad	0.0309	0.0255	-0.0054
52	105	Biased-100krad	-0.0609	0.0005	0.0614
53	105	Biased-100krad	-0.0687	-0.026	0.0427
54	105	Biased-100krad	-0.0298	-0.104	-0.0742

Test Statistics (nA)

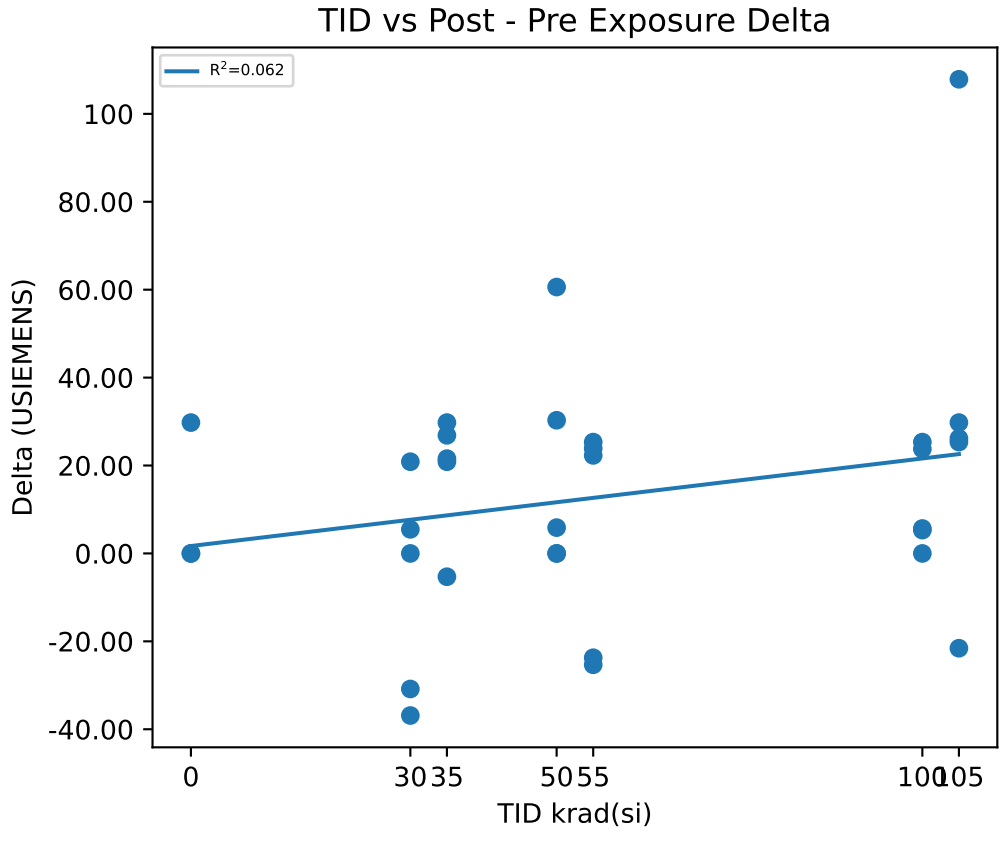
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0952	-0.075967	-0.0391	0.031937	-0.0603	-0.0041667	0.0707	0.067479	0.0162	0.0718	0.1643	0.080651
30	-0.1326	-0.08524	-0.0672	0.027491	-0.0245	-0.00574	0.0177	0.01605	0.0599	0.0795	0.1175	0.023745
35	-0.1668	-0.13444	-0.1139	0.020002	-0.0291	0.00144	0.0707	0.040714	0.0894	0.13588	0.1939	0.038155
50	-0.184	-0.11824	-0.0547	0.055098	-0.0525	-0.0151	0.027	0.029721	0.0178	0.10314	0.211	0.077136
55	-0.1092	-0.06376	-0.0205	0.032709	-0.0947	-0.01852	0.0536	0.061955	-0.0742	0.04524	0.1284	0.086612
100	-0.1513	-0.10954	-0.0781	0.033648	-0.0432	-0.00574	0.0364	0.034526	0.0349	0.1038	0.1611	0.053021
105	-0.1139	-0.04848	0.0309	0.053603	-0.104	-0.03506	0.0255	0.052631	-0.0742	0.01342	0.0614	0.054869

Device Test: 38.20 _EA|Transconductance/VSNS4/3/3///90.9/634//0///@EA_GM_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



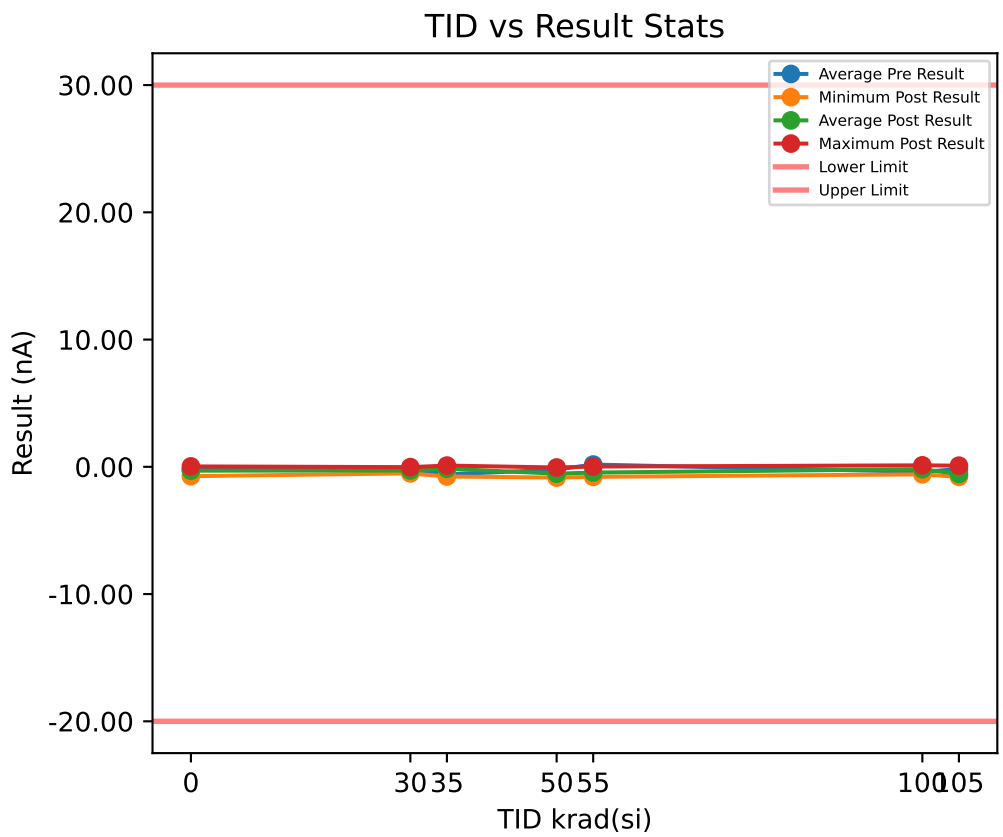
Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

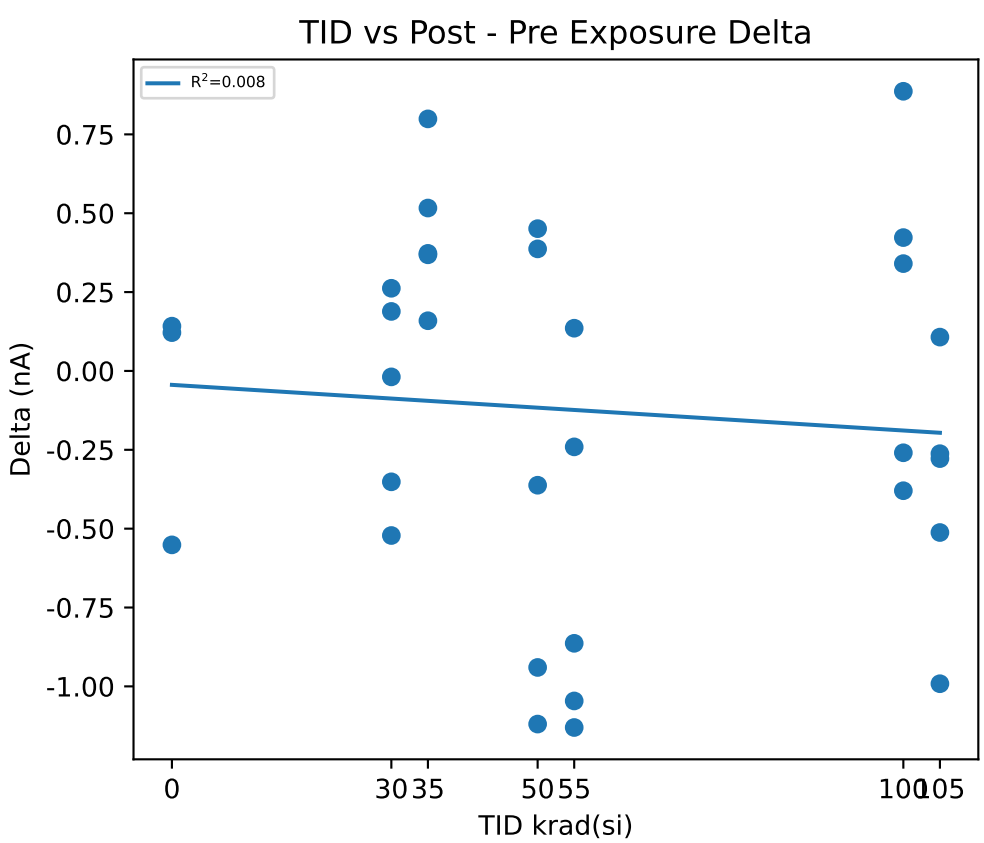
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1684.7	1684.7	0
2	0	CU2	1606.6	1606.6	0
3	0	CU3	1684.7	1714.5	29.766
11	30	Unbiased-30krad	1745.3	1714.5	-30.836
12	30	Unbiased-30krad	1745.3	1708.5	-36.873
13	30	Unbiased-30krad	1628.2	1628.2	0
14	30	Unbiased-30krad	1580.5	1601.3	20.864
15	30	Unbiased-30krad	1628.2	1633.7	5.4821
16	35	Biased-30krad	1601.3	1628.2	26.868
17	35	Biased-30krad	1580.5	1601.3	20.864
18	35	Biased-30krad	1606.6	1601.3	-5.3024
19	35	Biased-30krad	1684.7	1714.5	29.766
20	35	Biased-30krad	1606.6	1628.2	21.566
30	50	Unbiased-50krad	1745.3	1745.3	0
31	50	Unbiased-50krad	1684.7	1690.6	5.8702
32	50	Unbiased-50krad	1550.2	1580.5	30.297
33	50	Unbiased-50krad	1684.7	1684.7	0
34	50	Unbiased-50krad	1684.7	1745.3	60.602
40	55	Biased-50krad	1555.1	1580.5	25.328
41	55	Biased-50krad	1708.5	1684.7	-23.729
42	55	Biased-50krad	1690.6	1714.5	23.895
43	55	Biased-50krad	1633.7	1656	22.303
44	55	Biased-50krad	1580.5	1555.1	-25.328
45	100	Unbiased-100krad	1555.1	1580.5	25.328
46	100	Unbiased-100krad	1506.8	1530.6	23.767
47	100	Unbiased-100krad	1656	1661.7	5.6712
48	100	Unbiased-100krad	1714.5	1714.5	0
49	100	Unbiased-100krad	1601.3	1606.6	5.3024
50	105	Biased-100krad	1628.2	1606.6	-21.566
51	105	Biased-100krad	1555.1	1580.5	25.328
52	105	Biased-100krad	1606.6	1714.5	107.87
53	105	Biased-100krad	1580.5	1606.6	26.167
54	105	Biased-100krad	1684.7	1714.5	29.766

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1606.6	1658.7	1684.7	45.091	1606.6	1668.6	1714.5	55.709	0	9.9219	29.766	17.185
30	1580.5	1665.5	1745.3	75.434	1601.3	1657.2	1714.5	51.055	-36.873	-8.2727	20.864	24.666
35	1580.5	1616	1684.7	39.93	1601.3	1634.7	1714.5	46.582	-5.3024	18.752	29.766	13.948
50	1550.2	1669.9	1745.3	71.913	1580.5	1689.3	1745.3	67.356	0	19.354	60.602	26.23
55	1555.1	1633.7	1708.5	66.77	1555.1	1638.2	1714.5	68.073	-25.328	4.4939	25.328	26.521
100	1506.8	1606.8	1714.5	81.714	1530.6	1618.8	1714.5	71.397	0	12.014	25.328	11.673
105	1555.1	1611	1684.7	49.508	1580.5	1644.6	1714.5	64.745	-21.566	33.512	107.87	46.629

Device Test: 38.3 _EA|Leakage/VSNS3/3/3///90.9/634//0///@IVSNS_LKG





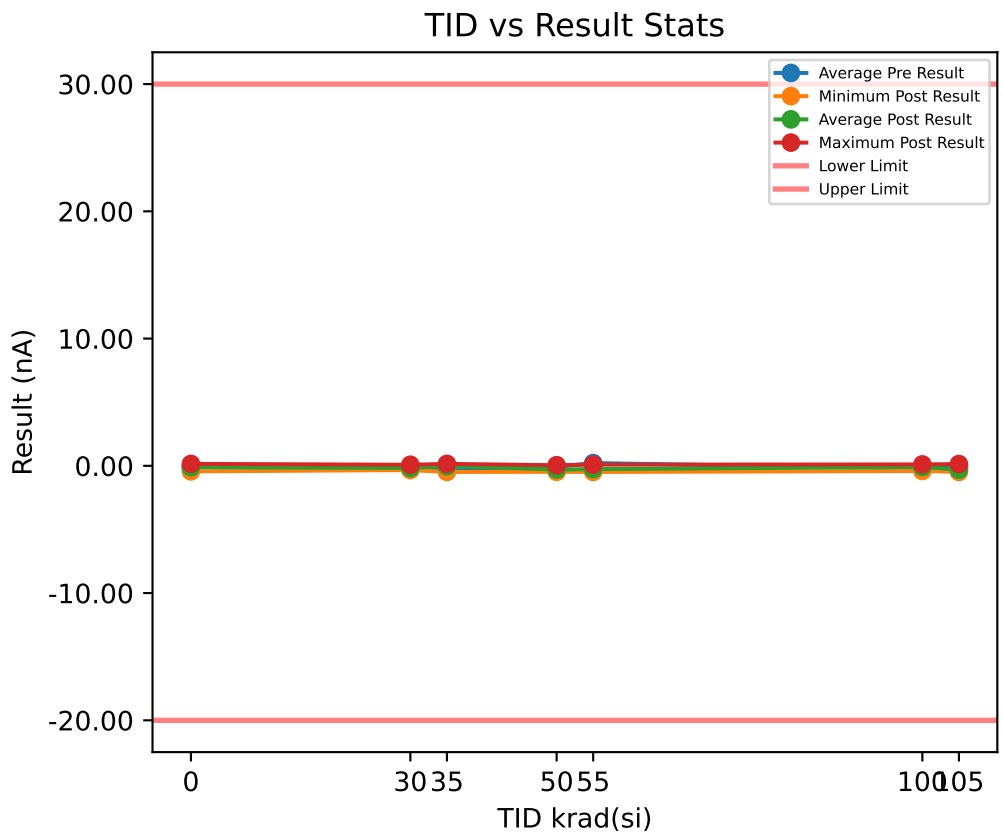
Test Results (Lower Limit = -20.0, Upper Limit = 30.0 (nA))

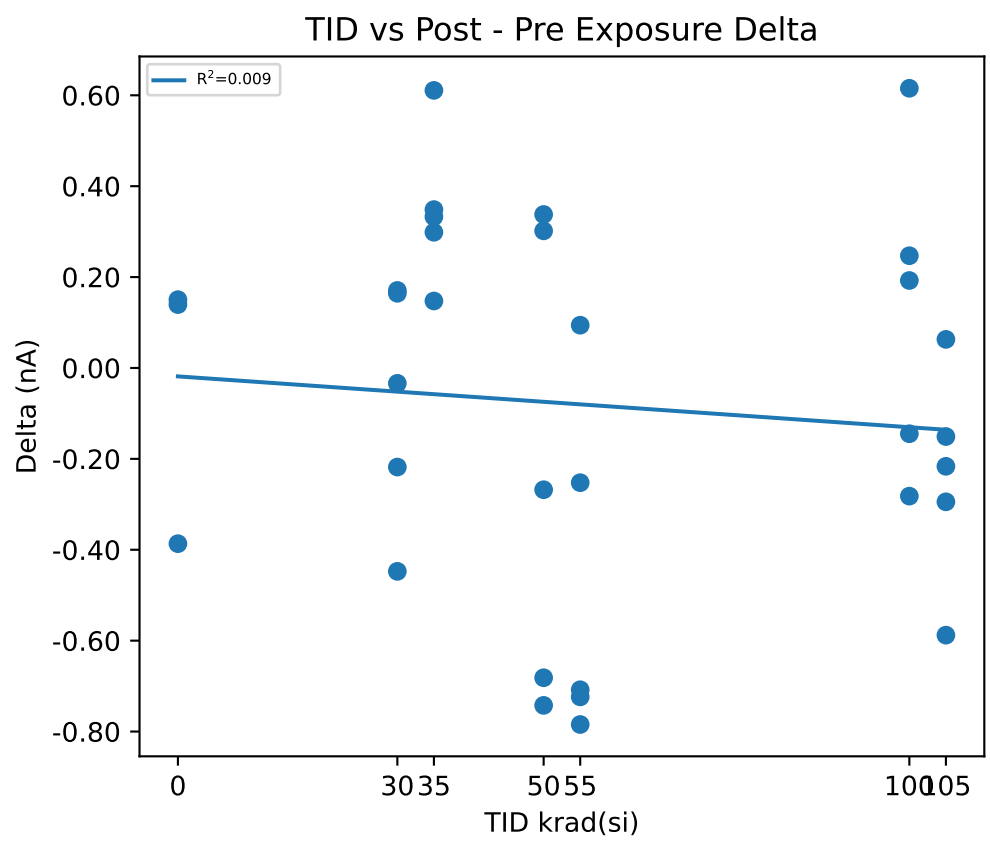
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.8789	-0.7369	0.142
2	0	CU2	0.3452	-0.2062	-0.5514
3	0	CU3	-0.0889	0.0326	0.1215
11	30	Unbiased-30krad	-0.4964	-0.5152	-0.0188
12	30	Unbiased-30krad	-0.0373	-0.3888	-0.3515
13	30	Unbiased-30krad	-0.2138	-0.0251	0.1887
14	30	Unbiased-30krad	-0.5916	-0.3295	0.2621
15	30	Unbiased-30krad	0.3358	-0.1859	-0.5217
16	35	Biased-30krad	-0.512	-0.1438	0.3682
17	35	Biased-30krad	-0.9195	-0.7603	0.1592
18	35	Biased-30krad	-0.4183	0.0982	0.5165
19	35	Biased-30krad	-0.3574	0.0154	0.3728
20	35	Biased-30krad	-0.7634	0.0357	0.7991
30	50	Unbiased-50krad	0.3015	-0.6385	-0.94
31	50	Unbiased-50krad	-0.4402	-0.0532	0.387
32	50	Unbiased-50krad	-0.8555	-0.4044	0.4511
33	50	Unbiased-50krad	0.2749	-0.8446	-1.1195
34	50	Unbiased-50krad	-0.3933	-0.7556	-0.3623
40	55	Biased-50krad	-0.1154	0.0201	0.1355
41	55	Biased-50krad	0.111	-0.1297	-0.2407
42	55	Biased-50krad	0.3405	-0.7899	-1.1304
43	55	Biased-50krad	0.2827	-0.5808	-0.8635
44	55	Biased-50krad	0.2734	-0.7728	-1.0462
45	100	Unbiased-100krad	-0.9117	-0.0251	0.8866
46	100	Unbiased-100krad	0.1813	-0.1984	-0.3797
47	100	Unbiased-100krad	-0.9305	-0.5902	0.3403
48	100	Unbiased-100krad	0.0157	-0.2437	-0.2594
49	100	Unbiased-100krad	-0.3059	0.1169	0.4228
50	105	Biased-100krad	-0.2762	-0.7884	-0.5122
51	105	Biased-100krad	-0.017	0.0903	0.1073
52	105	Biased-100krad	-0.4933	-0.7556	-0.2623
53	105	Biased-100krad	-0.498	-0.7759	-0.2779
54	105	Biased-100krad	0.3749	-0.6167	-0.9916

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.8789	-0.20753	0.3452	0.62061	-0.7369	-0.3035	0.0326	0.39387	-0.5514	-0.095967	0.142	0.39455
30	-0.5916	-0.20066	0.3358	0.37247	-0.5152	-0.2889	-0.0251	0.1891	-0.5217	-0.08824	0.2621	0.33965
35	-0.9195	-0.59412	-0.3574	0.23886	-0.7603	-0.15096	0.0982	0.35212	0.1592	0.44316	0.7991	0.23626
50	-0.8555	-0.22252	0.3015	0.49981	-0.8446	-0.53926	-0.0532	0.31793	-1.1195	-0.31674	0.4511	0.72797
55	-0.1154	0.17844	0.3405	0.1851	-0.7899	-0.45062	0.0201	0.37431	-1.1304	-0.62906	0.1355	0.55129
100	-0.9305	-0.39022	0.1813	0.51535	-0.5902	-0.1881	0.1169	0.26668	-0.3797	0.20212	0.8866	0.52149
105	-0.498	-0.18192	0.3749	0.36844	-0.7884	-0.56926	0.0903	0.37507	-0.9916	-0.38734	0.1073	0.40404

Device Test: 38.4 _EA|Leakage/VSNS4/3/3///90.9/634//0///@IVSNS_LKG





Test Results (Lower Limit = -20.0, Upper Limit = 30.0 (nA))

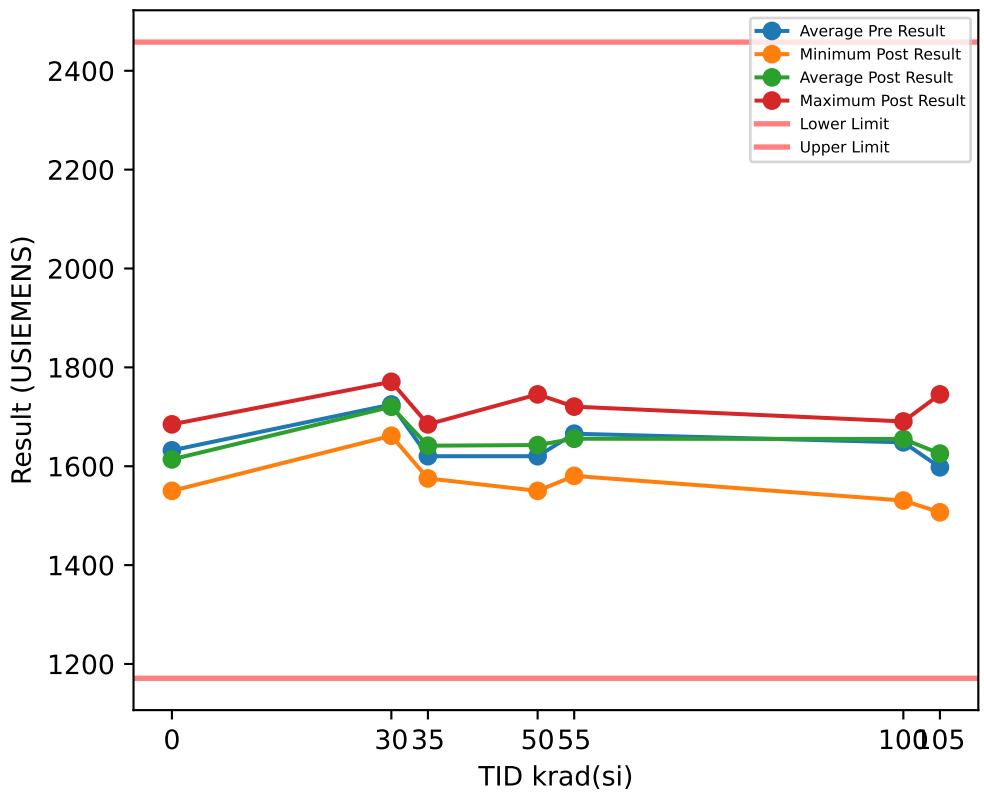
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.576	-0.4365	0.1395
2	0	CU2	0.3246	-0.062	-0.3866
3	0	CU3	0.0015	0.1518	0.1503
11	30	Unbiased-30krad	-0.2982	-0.332	-0.0338
12	30	Unbiased-30krad	-0.0001	-0.2181	-0.218
13	30	Unbiased-30krad	-0.0812	0.0831	0.1643
14	30	Unbiased-30krad	-0.409	-0.2384	0.1706
15	30	Unbiased-30krad	0.3168	-0.1307	-0.4475
16	35	Biased-30krad	-0.2873	0.0113	0.2986
17	35	Biased-30krad	-0.6307	-0.4833	0.1474
18	35	Biased-30krad	-0.2295	0.1034	0.3329
19	35	Biased-30krad	-0.1967	0.1518	0.3485
20	35	Biased-30krad	-0.5386	0.0722	0.6108
30	50	Unbiased-50krad	0.2981	-0.3835	-0.6816
31	50	Unbiased-50krad	-0.2545	0.0472	0.3017
32	50	Unbiased-50krad	-0.5261	-0.1884	0.3377
33	50	Unbiased-50krad	0.3059	-0.4365	-0.7424
34	50	Unbiased-50krad	-0.2061	-0.474	-0.2679
40	55	Biased-50krad	-0.0032	0.0909	0.0941
41	55	Biased-50krad	0.2341	-0.0183	-0.2524
42	55	Biased-50krad	0.3012	-0.4833	-0.7845
43	55	Biased-50krad	0.309	-0.4147	-0.7237
44	55	Biased-50krad	0.2356	-0.4724	-0.708
45	100	Unbiased-100krad	-0.5432	0.0722	0.6154
46	100	Unbiased-100krad	0.1482	-0.1338	-0.282
47	100	Unbiased-100krad	-0.5994	-0.4069	0.1925
48	100	Unbiased-100krad	0.0468	-0.0979	-0.1447
49	100	Unbiased-100krad	-0.1374	0.1096	0.247
50	105	Biased-100krad	-0.1764	-0.4709	-0.2945
51	105	Biased-100krad	0.0764	0.1393	0.0629
52	105	Biased-100krad	-0.2966	-0.4475	-0.1509
53	105	Biased-100krad	-0.2638	-0.4802	-0.2164
54	105	Biased-100krad	0.3137	-0.2742	-0.5879

Test Statistics (nA)

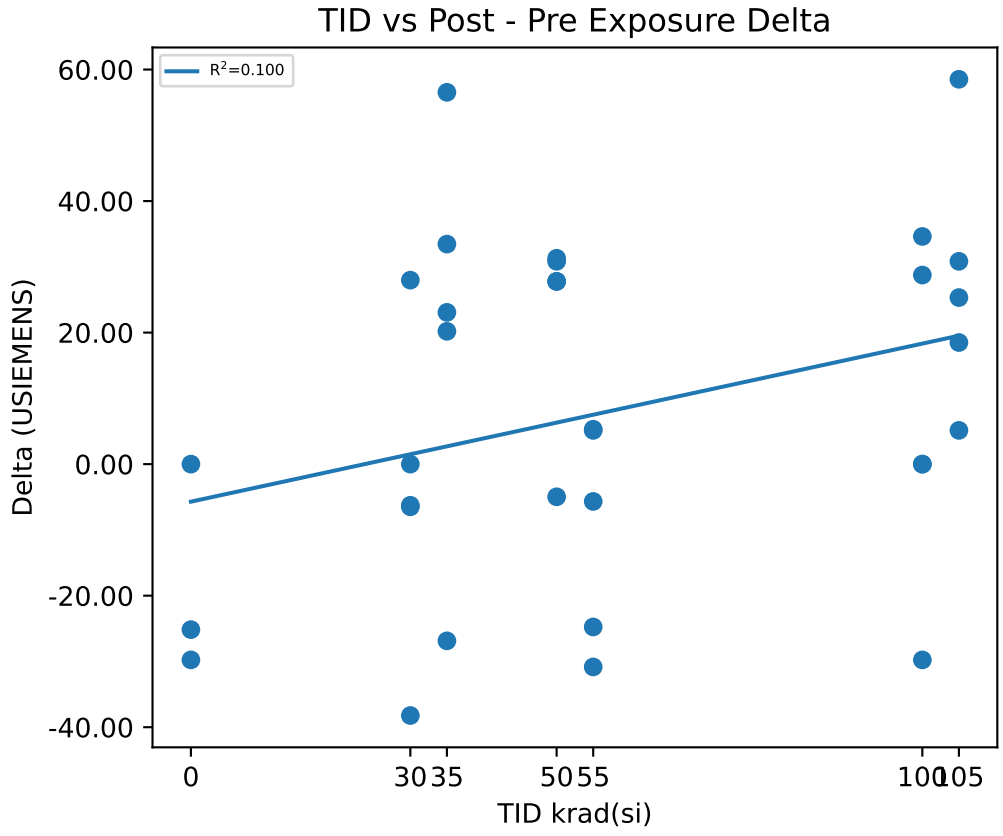
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.576	-0.0833	0.3246	0.45625	-0.4365	-0.11557	0.1518	0.29779	-0.3866	-0.032267	0.1503	0.30691
30	-0.409	-0.09434	0.3168	0.28225	-0.332	-0.16722	0.0831	0.15716	-0.4475	-0.07288	0.1706	0.26385
35	-0.6307	-0.37656	-0.1967	0.19544	-0.4833	-0.02892	0.1518	0.25907	0.1474	0.34764	0.6108	0.16731
50	-0.5261	-0.07654	0.3059	0.36646	-0.474	-0.28704	0.0472	0.21682	-0.7424	-0.2105	0.3377	0.51745
55	-0.0032	0.21534	0.309	0.12715	-0.4833	-0.25956	0.0909	0.27407	-0.7845	-0.4749	0.0941	0.38254
100	-0.5994	-0.217	0.1482	0.33983	-0.4069	-0.09136	0.1096	0.20527	-0.282	0.12564	0.6154	0.35296
105	-0.2966	-0.06934	0.3137	0.25927	-0.4802	-0.3067	0.1393	0.26309	-0.5879	-0.23736	0.0629	0.23676

Device Test: 38.5 _EA|Transconductance/VSNS1/3/3///90.9/634//0///@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



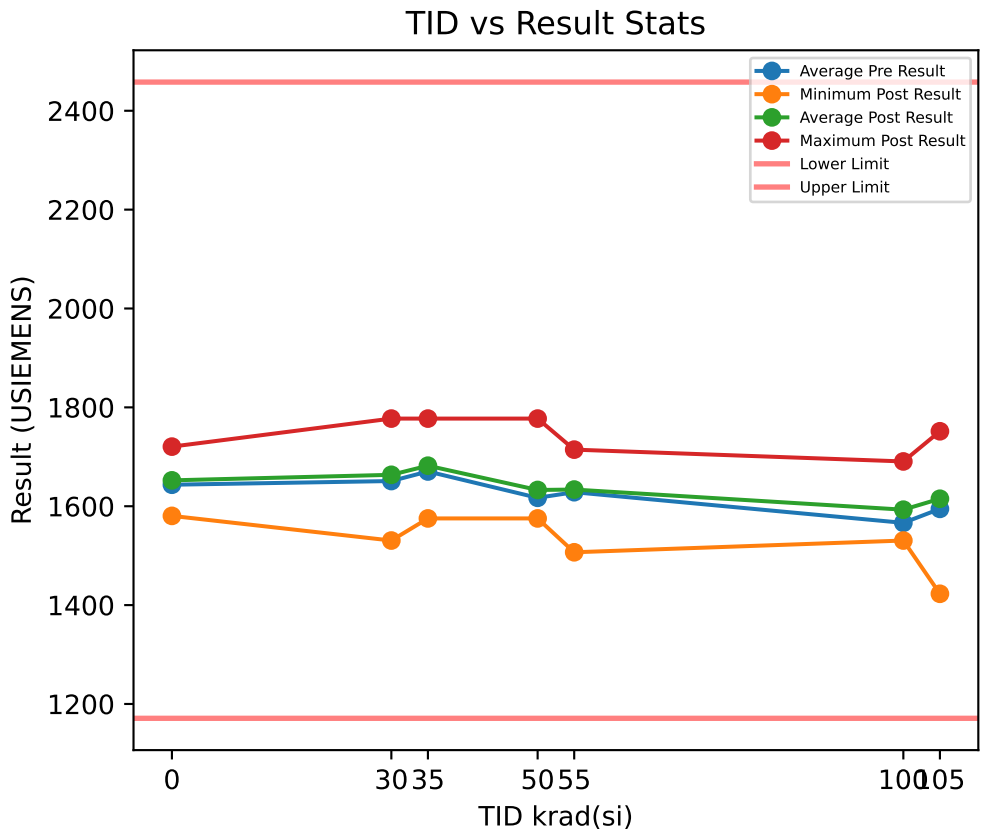
Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

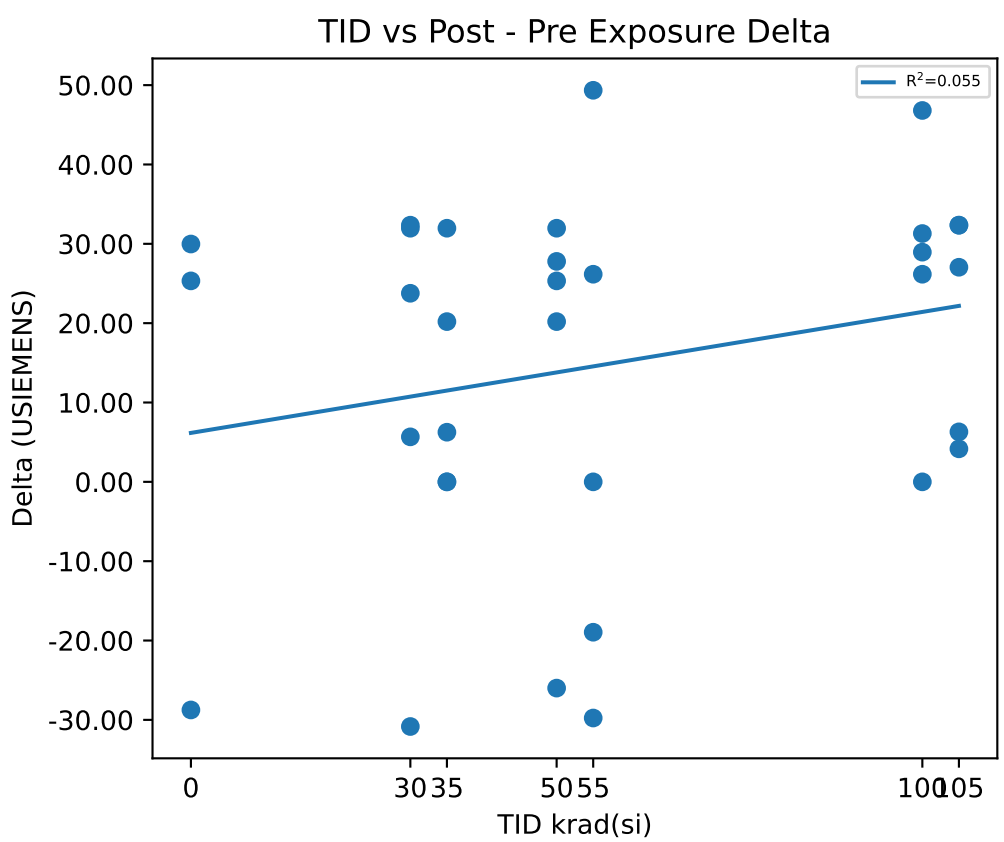
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1714.5	1684.7	-29.766
2	0	CU2	1606.6	1606.6	0
3	0	CU3	1575.3	1550.2	-25.165
11	30	Unbiased-30krad	1633.7	1661.7	27.974
12	30	Unbiased-30krad	1745.3	1739.1	-6.2557
13	30	Unbiased-30krad	1777.3	1770.8	-6.4865
14	30	Unbiased-30krad	1690.6	1690.6	0
15	30	Unbiased-30krad	1777.3	1739.1	-38.222
16	35	Biased-30krad	1555.1	1575.3	20.197
17	35	Biased-30krad	1661.7	1684.7	23.079
18	35	Biased-30krad	1628.2	1661.7	33.456
19	35	Biased-30krad	1628.2	1684.7	56.535
20	35	Biased-30krad	1628.2	1601.3	-26.868
30	50	Unbiased-50krad	1575.3	1606.6	31.298
31	50	Unbiased-50krad	1628.2	1656	27.785
32	50	Unbiased-50krad	1628.2	1656	27.785
33	50	Unbiased-50krad	1555.1	1550.2	-4.9685
34	50	Unbiased-50krad	1714.5	1745.3	30.836
40	55	Biased-50krad	1745.3	1714.5	-30.836
41	55	Biased-50krad	1575.3	1580.5	5.1314
42	55	Biased-50krad	1745.3	1720.6	-24.757
43	55	Biased-50krad	1661.7	1656	-5.6712
44	55	Biased-50krad	1601.3	1606.6	5.3024
45	100	Unbiased-100krad	1656	1690.6	34.62
46	100	Unbiased-100krad	1530.6	1530.6	0
47	100	Unbiased-100krad	1656	1684.7	28.75
48	100	Unbiased-100krad	1714.5	1684.7	-29.766
49	100	Unbiased-100krad	1684.7	1684.7	0
50	105	Biased-100krad	1656	1714.5	58.515
51	105	Biased-100krad	1575.3	1580.5	5.1314
52	105	Biased-100krad	1555.1	1580.5	25.328
53	105	Biased-100krad	1488.4	1506.8	18.489
54	105	Biased-100krad	1714.5	1745.3	30.836

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1632.2	1714.5	73.008	1550.2	1613.9	1684.7	67.571	-29.766	-18.31	0	16.023
30	1633.7	1724.9	1777.3	62.062	1661.7	1720.3	1770.8	43.527	-38.222	-4.598	27.974	23.553
35	1555.1	1620.3	1661.7	39.19	1575.3	1641.6	1684.7	50.339	-26.868	21.28	56.535	30.471
50	1555.1	1620.3	1714.5	61.778	1550.2	1642.8	1745.3	72.024	-4.9685	22.547	31.298	15.47
55	1575.3	1665.8	1745.3	79.072	1580.5	1655.6	1720.6	62.718	-30.836	-10.166	5.3024	16.835
100	1530.6	1648.4	1714.5	70.141	1530.6	1655.1	1690.6	69.629	-29.766	6.7208	34.62	25.91
105	1488.4	1597.9	1714.5	88.469	1506.8	1625.5	1745.3	100.52	5.1314	27.66	58.515	19.744

Device Test: 38.6 _EA|Transconductance/VSNS2/3/3///90.9/634//0///@EA_GM





Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

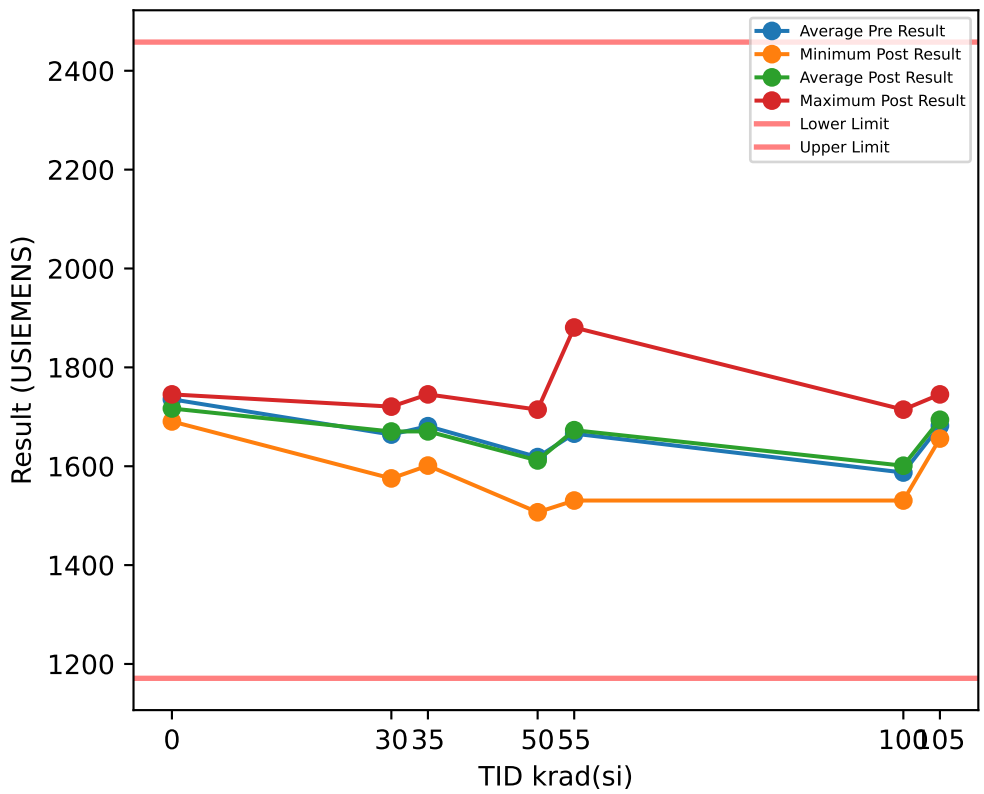
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1690.6	1720.6	29.975
2	0	CU2	1555.1	1580.5	25.328
3	0	CU3	1684.7	1656	-28.75
11	30	Unbiased-30krad	1656	1661.7	5.6712
12	30	Unbiased-30krad	1745.3	1714.5	-30.836
13	30	Unbiased-30krad	1745.3	1777.3	31.966
14	30	Unbiased-30krad	1506.8	1530.6	23.767
15	30	Unbiased-30krad	1601.3	1633.7	32.35
16	35	Biased-30krad	1656	1656	0
17	35	Biased-30krad	1739.1	1745.3	6.2557
18	35	Biased-30krad	1656	1656	0
19	35	Biased-30krad	1745.3	1777.3	31.966
20	35	Biased-30krad	1555.1	1575.3	20.197
30	50	Unbiased-50krad	1555.1	1580.5	25.328
31	50	Unbiased-50krad	1555.1	1575.3	20.197
32	50	Unbiased-50krad	1601.3	1575.3	-25.996
33	50	Unbiased-50krad	1628.2	1656	27.785
34	50	Unbiased-50krad	1745.3	1777.3	31.966
40	55	Biased-50krad	1580.5	1606.6	26.167
41	55	Biased-50krad	1714.5	1684.7	-29.766
42	55	Biased-50krad	1714.5	1714.5	0
43	55	Biased-50krad	1606.6	1656	49.351
44	55	Biased-50krad	1525.8	1506.8	-18.954
45	100	Unbiased-100krad	1530.6	1530.6	0
46	100	Unbiased-100krad	1580.5	1606.6	26.167
47	100	Unbiased-100krad	1575.3	1606.6	31.298
48	100	Unbiased-100krad	1661.7	1690.6	28.949
49	100	Unbiased-100krad	1483.8	1530.6	46.808
50	105	Biased-100krad	1601.3	1633.7	32.35
51	105	Biased-100krad	1418.7	1422.9	4.1605
52	105	Biased-100krad	1606.6	1633.7	27.048
53	105	Biased-100krad	1601.3	1633.7	32.35
54	105	Biased-100krad	1745.3	1751.6	6.3009

Test Statistics (USIEMENS)

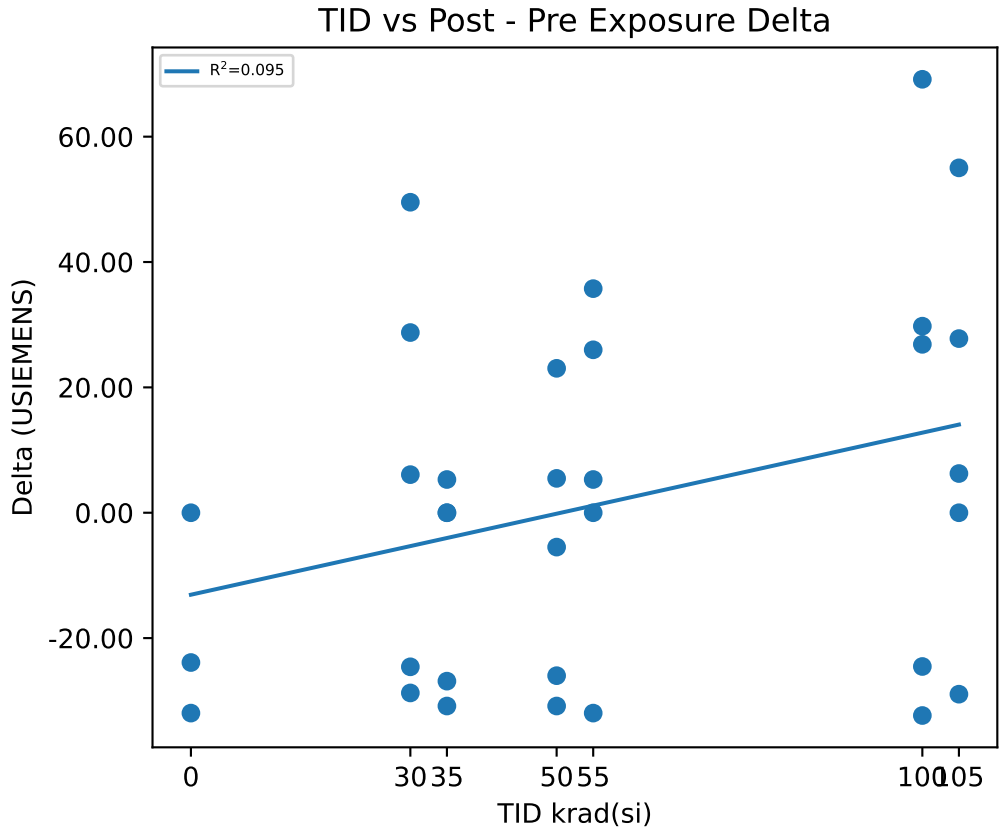
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1555.1	1643.5	1690.6	76.573	1580.5	1652.3	1720.6	70.127	-28.75	8.8512	29.975	32.646
30	1506.8	1651	1745.3	101.33	1530.6	1663.6	1777.3	92.337	-30.836	12.584	32.35	26.573
35	1555.1	1670.3	1745.3	77.513	1575.3	1682	1777.3	80.351	0	11.684	31.966	14.021
50	1555.1	1617	1745.3	78.254	1575.3	1632.9	1777.3	87.695	-25.996	15.856	31.966	23.78
55	1525.8	1628.4	1714.5	83.853	1506.8	1633.7	1714.5	81.325	-29.766	5.3595	49.351	32.488
100	1483.8	1566.4	1661.7	66.058	1530.6	1593	1690.6	66.49	0	26.644	46.808	16.909
105	1418.7	1594.7	1745.3	116.07	1422.9	1615.1	1751.6	118.98	4.1605	20.442	32.35	14.074

Device Test: 38.7 _EA|Transconductance/VSNS3/3/3///90.9/634//0///@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

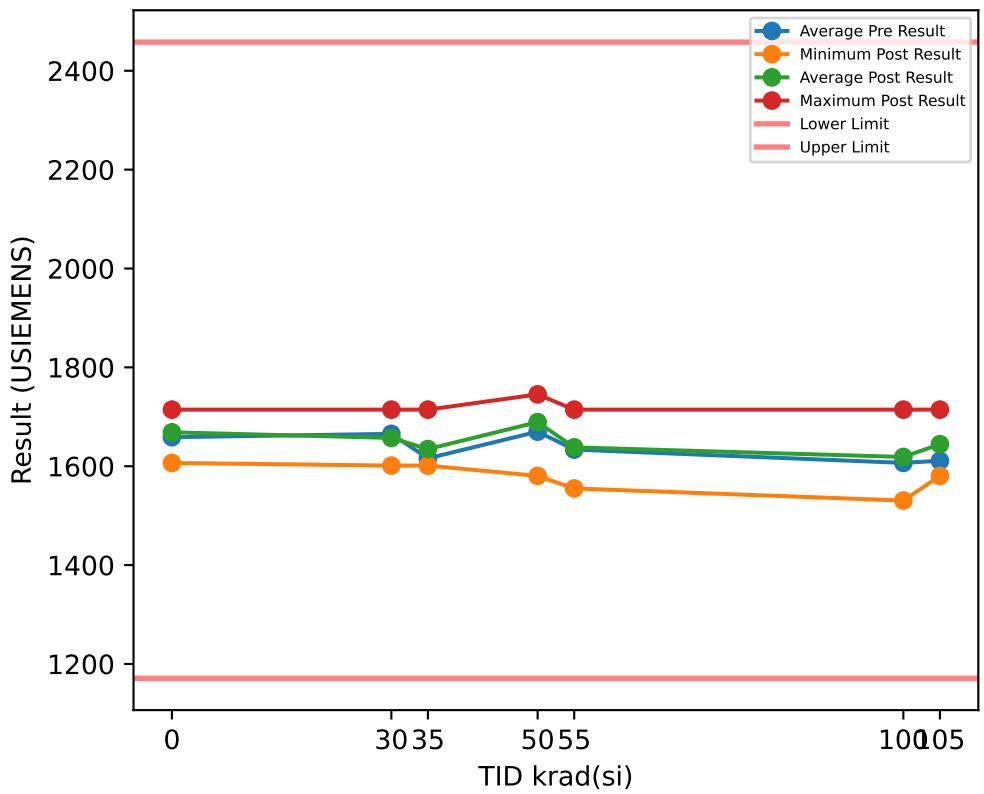
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1777.3	1745.3	-31.966
2	0	CU2	1714.5	1690.6	-23.895
3	0	CU3	1714.5	1714.5	0
11	30	Unbiased-30krad	1714.5	1720.6	6.0798
12	30	Unbiased-30krad	1684.7	1656	-28.75
13	30	Unbiased-30krad	1656	1684.7	28.75
14	30	Unbiased-30krad	1525.8	1575.3	49.539
15	30	Unbiased-30krad	1739.1	1714.5	-24.581
16	35	Biased-30krad	1628.2	1601.3	-26.868
17	35	Biased-30krad	1684.7	1684.7	0
18	35	Biased-30krad	1745.3	1745.3	0
19	35	Biased-30krad	1745.3	1714.5	-30.836
20	35	Biased-30krad	1601.3	1606.6	5.3024
30	50	Unbiased-50krad	1483.8	1506.8	23.04
31	50	Unbiased-50krad	1628.2	1633.7	5.4821
32	50	Unbiased-50krad	1601.3	1575.3	-25.996
33	50	Unbiased-50krad	1633.7	1628.2	-5.4821
34	50	Unbiased-50krad	1745.3	1714.5	-30.836
40	55	Biased-50krad	1777.3	1745.3	-31.966
41	55	Biased-50krad	1575.3	1601.3	25.996
42	55	Biased-50krad	1844.9	1880.6	35.754
43	55	Biased-50krad	1530.6	1530.6	0
44	55	Biased-50krad	1601.3	1606.6	5.3024
45	100	Unbiased-100krad	1555.1	1530.6	-24.529
46	100	Unbiased-100krad	1461.5	1530.6	69.154
47	100	Unbiased-100krad	1633.7	1601.3	-32.35
48	100	Unbiased-100krad	1684.7	1714.5	29.766
49	100	Unbiased-100krad	1601.3	1628.2	26.868
50	105	Biased-100krad	1739.1	1745.3	6.2557
51	105	Biased-100krad	1628.2	1656	27.785
52	105	Biased-100krad	1690.6	1661.7	-28.949
53	105	Biased-100krad	1606.6	1661.7	55.022
54	105	Biased-100krad	1745.3	1745.3	0

Test Statistics (USIEMENS)

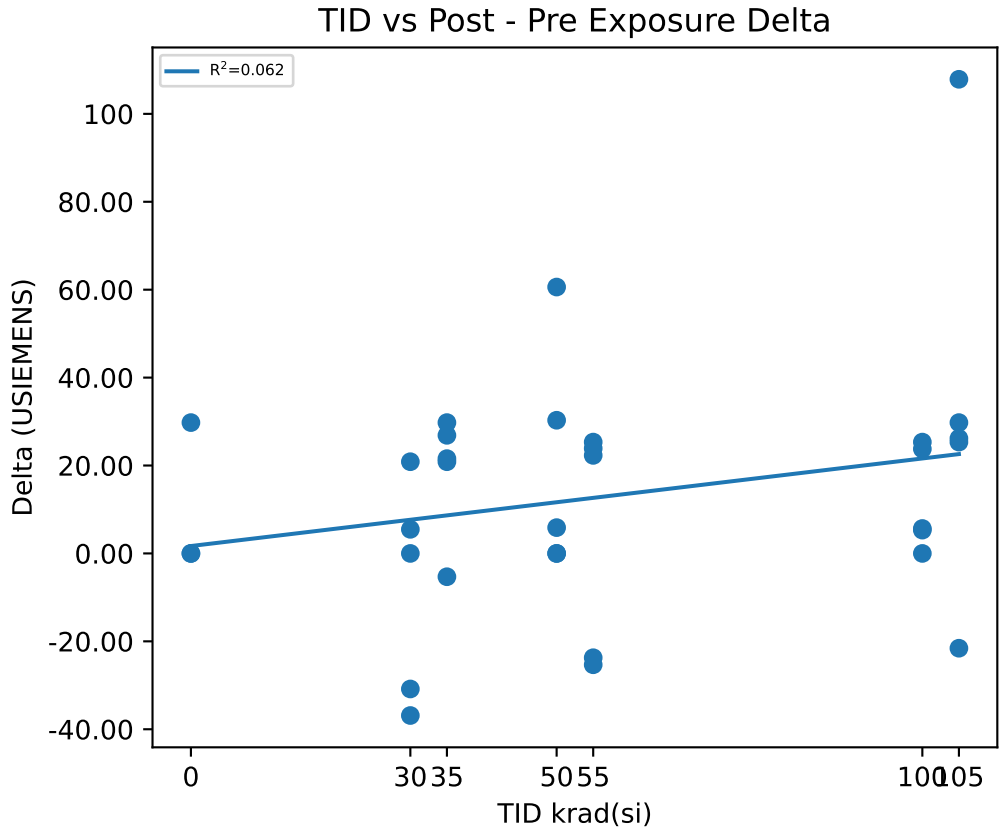
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1714.5	1735.4	1777.3	36.259	1690.6	1716.8	1745.3	27.439	-31.966	-18.62	0	16.623
30	1525.8	1664	1739.1	83.339	1575.3	1670.2	1720.6	58.977	-28.75	6.2076	49.539	33.748
35	1601.3	1681	1745.3	66.006	1601.3	1670.5	1745.3	64.425	-30.836	-10.48	5.3024	16.968
50	1483.8	1618.5	1745.3	93.341	1506.8	1611.7	1714.5	76.878	-30.836	-6.7583	23.04	22.301
55	1530.6	1665.9	1844.9	137.04	1530.6	1672.9	1880.6	139.79	-31.966	7.0171	35.754	26.258
100	1461.5	1587.3	1684.7	84.724	1530.6	1601.1	1714.5	76.7	-32.35	13.782	69.154	42.097
105	1606.6	1682	1745.3	63.084	1656	1694	1745.3	46.926	-28.949	12.023	55.022	31.44

Device Test: 38.8 _EA|Transconductance/VSNS4/3/3///90.9/634//0///@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

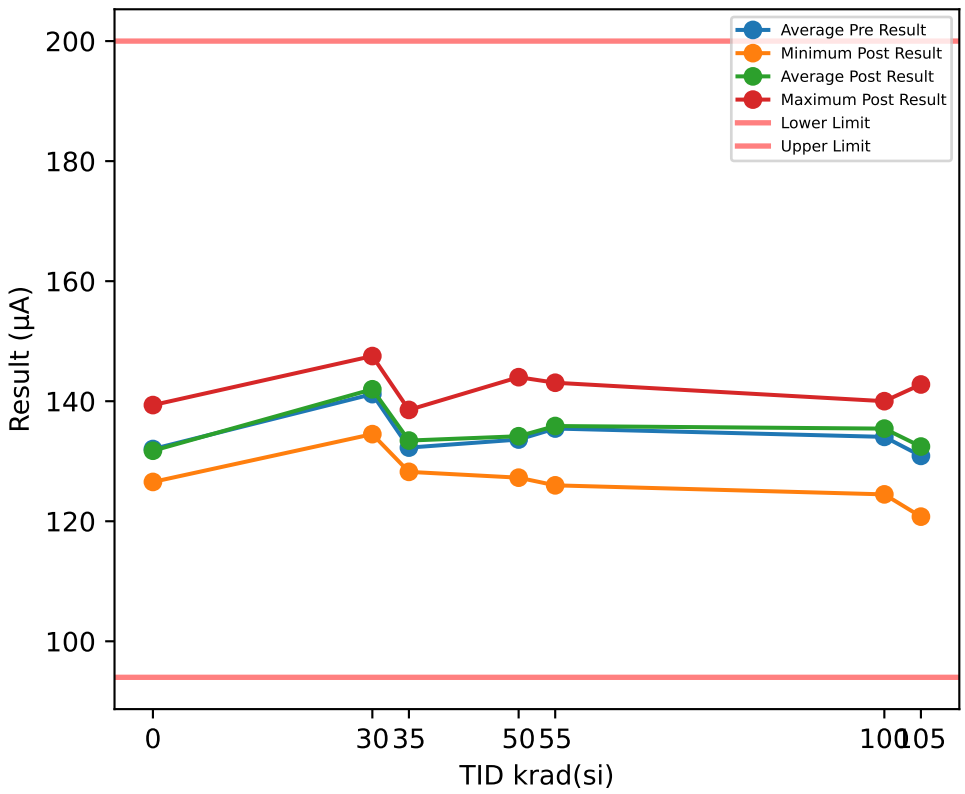
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1684.7	1684.7	0
2	0	CU2	1606.6	1606.6	0
3	0	CU3	1684.7	1714.5	29.766
11	30	Unbiased-30krad	1745.3	1714.5	-30.836
12	30	Unbiased-30krad	1745.3	1708.5	-36.873
13	30	Unbiased-30krad	1628.2	1628.2	0
14	30	Unbiased-30krad	1580.5	1601.3	20.864
15	30	Unbiased-30krad	1628.2	1633.7	5.4821
16	35	Biased-30krad	1601.3	1628.2	26.868
17	35	Biased-30krad	1580.5	1601.3	20.864
18	35	Biased-30krad	1606.6	1601.3	-5.3024
19	35	Biased-30krad	1684.7	1714.5	29.766
20	35	Biased-30krad	1606.6	1628.2	21.566
30	50	Unbiased-50krad	1745.3	1745.3	0
31	50	Unbiased-50krad	1684.7	1690.6	5.8702
32	50	Unbiased-50krad	1550.2	1580.5	30.297
33	50	Unbiased-50krad	1684.7	1684.7	0
34	50	Unbiased-50krad	1684.7	1745.3	60.602
40	55	Biased-50krad	1555.1	1580.5	25.328
41	55	Biased-50krad	1708.5	1684.7	-23.729
42	55	Biased-50krad	1690.6	1714.5	23.895
43	55	Biased-50krad	1633.7	1656	22.303
44	55	Biased-50krad	1580.5	1555.1	-25.328
45	100	Unbiased-100krad	1555.1	1580.5	25.328
46	100	Unbiased-100krad	1506.8	1530.6	23.767
47	100	Unbiased-100krad	1656	1661.7	5.6712
48	100	Unbiased-100krad	1714.5	1714.5	0
49	100	Unbiased-100krad	1601.3	1606.6	5.3024
50	105	Biased-100krad	1628.2	1606.6	-21.566
51	105	Biased-100krad	1555.1	1580.5	25.328
52	105	Biased-100krad	1606.6	1714.5	107.87
53	105	Biased-100krad	1580.5	1606.6	26.167
54	105	Biased-100krad	1684.7	1714.5	29.766

Test Statistics (USIEMENS)

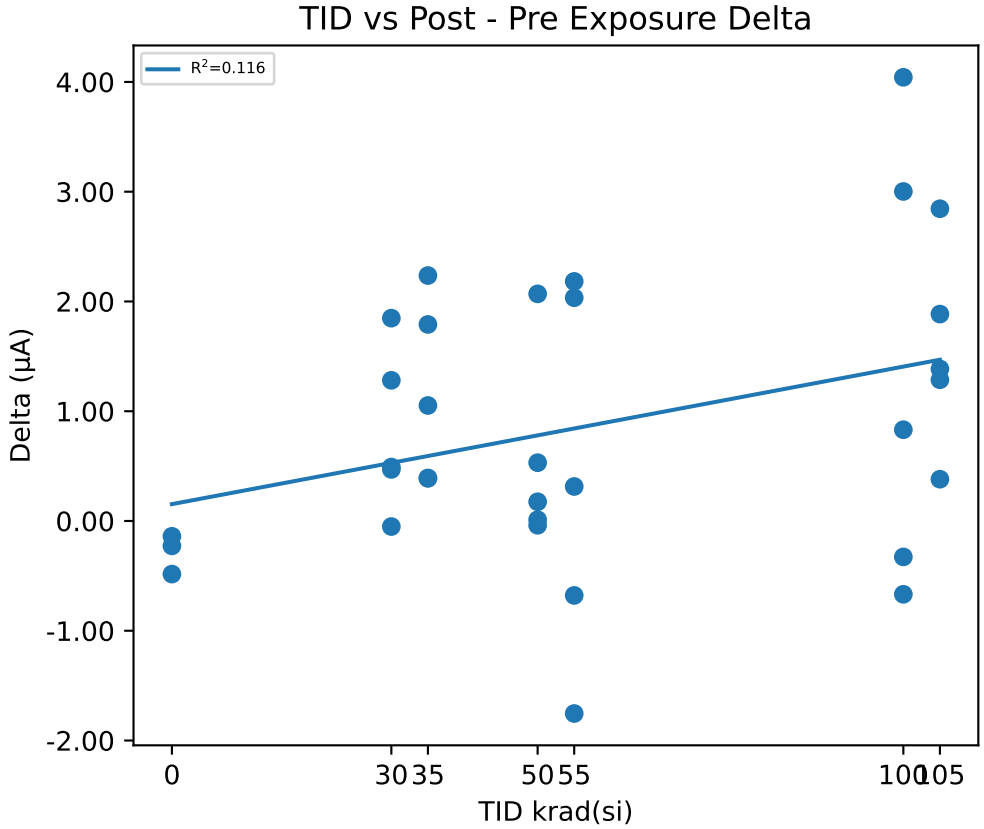
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1606.6	1658.7	1684.7	45.091	1606.6	1668.6	1714.5	55.709	0	9.9219	29.766	17.185
30	1580.5	1665.5	1745.3	75.434	1601.3	1657.2	1714.5	51.055	-36.873	-8.2727	20.864	24.666
35	1580.5	1616	1684.7	39.93	1601.3	1634.7	1714.5	46.582	-5.3024	18.752	29.766	13.948
50	1550.2	1669.9	1745.3	71.913	1580.5	1689.3	1745.3	67.356	0	19.354	60.602	26.23
55	1555.1	1633.7	1708.5	66.77	1555.1	1638.2	1714.5	68.073	-25.328	4.4939	25.328	26.521
100	1506.8	1606.8	1714.5	81.714	1530.6	1618.8	1714.5	71.397	0	12.014	25.328	11.673
105	1555.1	1611	1684.7	49.508	1580.5	1644.6	1714.5	64.745	-21.566	33.512	107.87	46.629

Device Test: 38.9 _EA|SourceCurrent/COMP1/3/3///90.9/634//0///@EA_SOURCE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



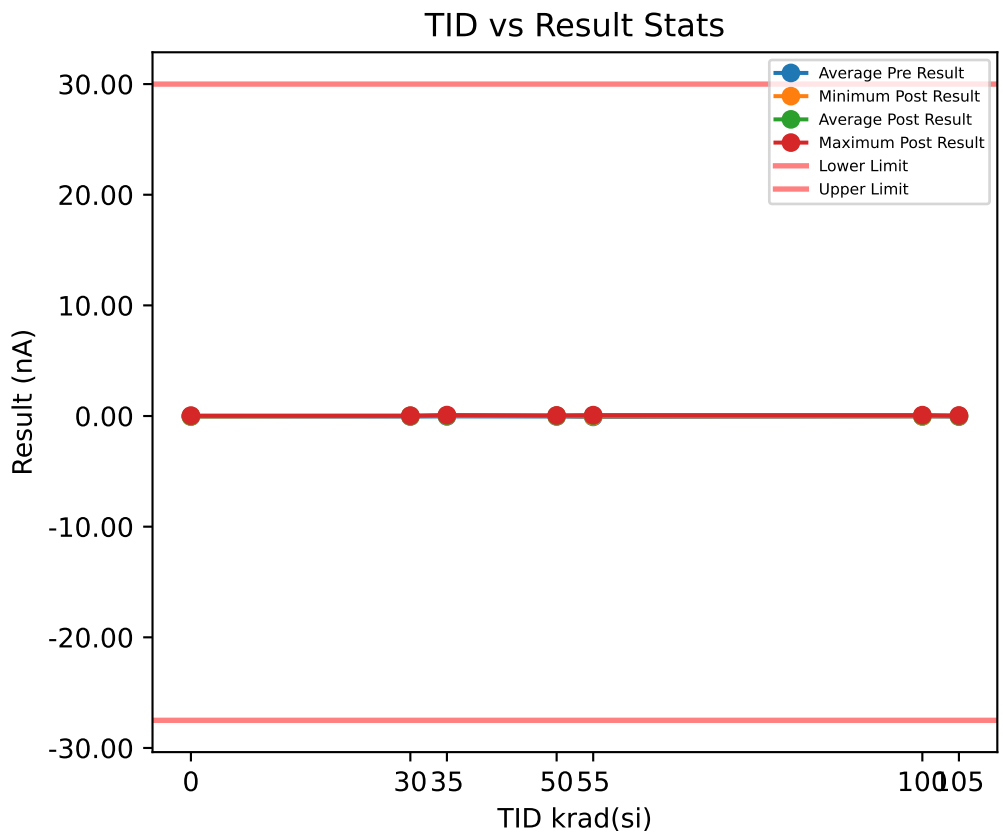
Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

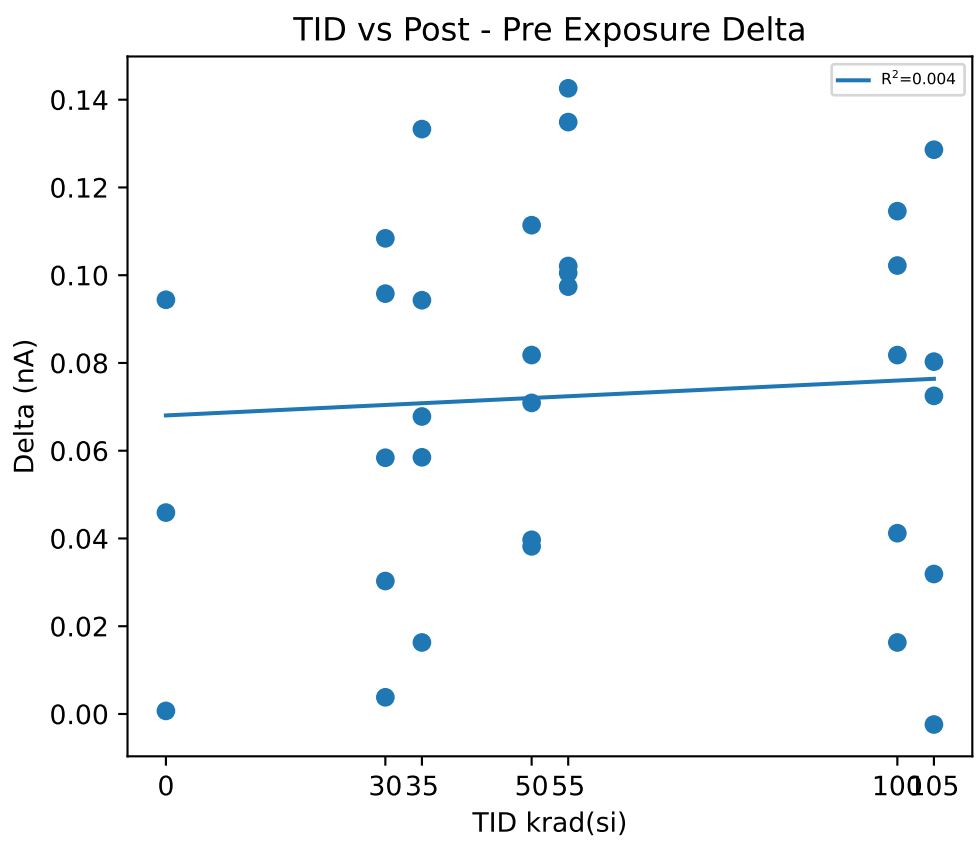
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	139.84	139.36	-0.4837
2	0	CU2	129.57	129.35	-0.2267
3	0	CU3	126.69	126.55	-0.1395
11	30	Unbiased-30krad	132.67	134.51	1.8479
12	30	Unbiased-30krad	145.01	145.48	0.4698
13	30	Unbiased-30krad	146.24	147.52	1.2816
14	30	Unbiased-30krad	137.38	137.33	-0.0507
15	30	Unbiased-30krad	144.6	145.09	0.4914
16	35	Biased-30krad	126.44	128.23	1.7907
17	35	Biased-30krad	136.31	138.55	2.2362
18	35	Biased-30krad	131.72	132.77	1.0524
19	35	Biased-30krad	135.74	136.13	0.3887
20	35	Biased-30krad	131.14	131.53	0.3916
30	50	Unbiased-50krad	130.4	130.58	0.1752
31	50	Unbiased-50krad	134.96	135.49	0.5311
32	50	Unbiased-50krad	133.48	133.49	0.0118
33	50	Unbiased-50krad	127.3	127.26	-0.039
34	50	Unbiased-50krad	141.93	144	2.0693
40	55	Biased-50krad	143.76	143.08	-0.6782
41	55	Biased-50krad	125.67	125.98	0.3143
42	55	Biased-50krad	143.63	141.87	-1.754
43	55	Biased-50krad	132.95	135.13	2.1828
44	55	Biased-50krad	131.24	133.27	2.0341
45	100	Unbiased-100krad	135.96	140.01	4.0424
46	100	Unbiased-100krad	124.81	124.48	-0.3272
47	100	Unbiased-100krad	134.87	137.87	3.0022
48	100	Unbiased-100krad	137.32	138.15	0.8315
49	100	Unbiased-100krad	137.33	136.66	-0.668
50	105	Biased-100krad	138.35	139.74	1.3855
51	105	Biased-100krad	126.02	128.86	2.8448
52	105	Biased-100krad	128.19	130.08	1.8851
53	105	Biased-100krad	120.39	120.77	0.3806
54	105	Biased-100krad	141.5	142.79	1.2867

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.69	132.03	139.84	6.9123	126.55	131.75	139.36	6.7335	-0.4837	-0.2833	-0.1395	0.17894
30	132.67	141.18	146.24	5.8939	134.51	141.99	147.52	5.7022	-0.0507	0.808	1.8479	0.75128
35	126.44	132.27	136.31	3.9985	128.23	133.44	138.55	4.0172	0.3887	1.1719	2.2362	0.82949
50	127.3	133.61	141.93	5.5051	127.26	134.16	144	6.3153	-0.039	0.54968	2.0693	0.87831
55	125.67	135.45	143.76	7.9921	125.98	135.87	143.08	6.9465	-1.754	0.4198	2.1828	1.7071
100	124.81	134.06	137.33	5.2742	124.48	135.43	140.01	6.2404	-0.668	1.3762	4.0424	2.0694
105	120.39	130.89	141.5	8.7981	120.77	132.45	142.79	8.8737	0.3806	1.5565	2.8448	0.90173

Device Test: 39.1 _EA|Leakage/VSNS1/7/7///90.9/634//0///@IVSNS_LKG





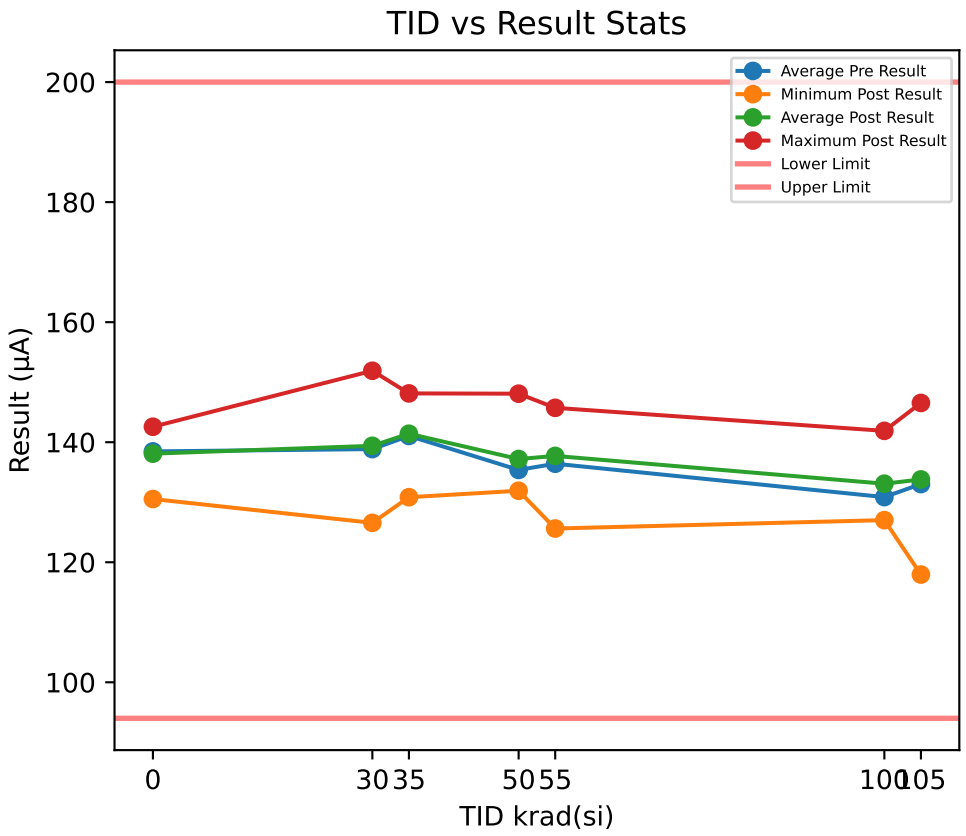
Test Results (Lower Limit = -27.5, Upper Limit = 30.0 (nA))

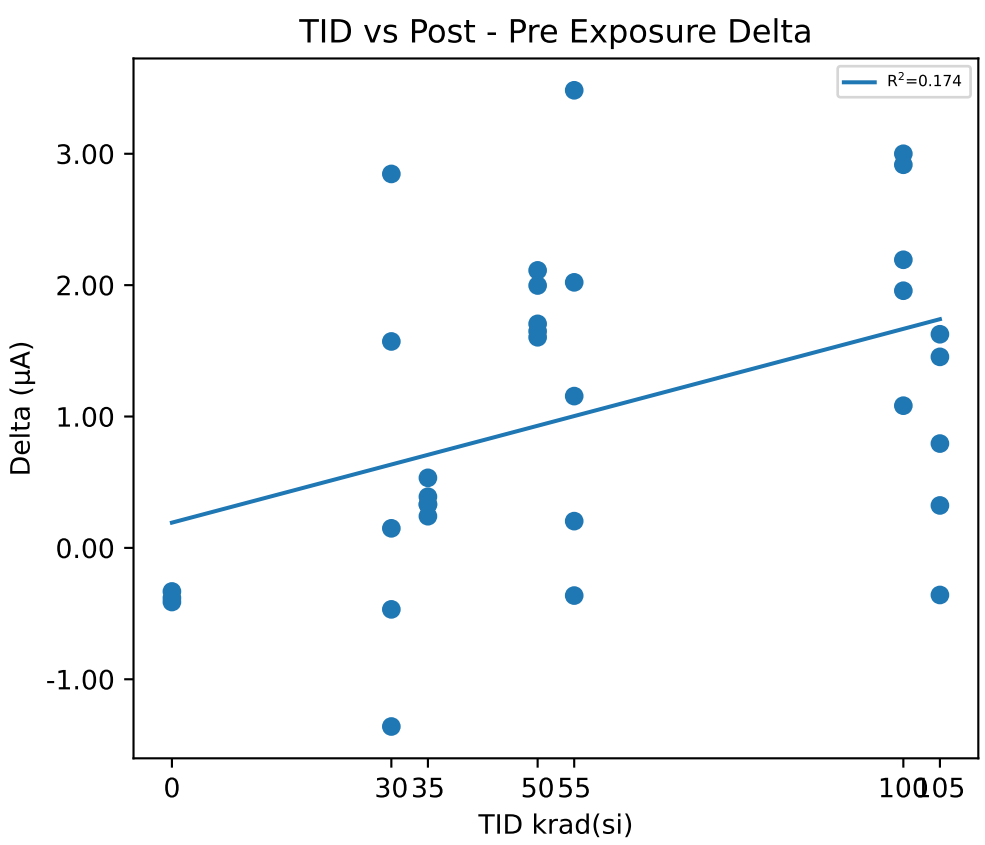
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.0118	-0.0111	0.0007
2	0	CU2	-0.0571	0.0373	0.0944
3	0	CU3	-0.0836	-0.0377	0.0459
11	30	Unbiased-30krad	-0.0742	0.0216	0.0958
12	30	Unbiased-30krad	-0.0149	-0.0111	0.0038
13	30	Unbiased-30krad	-0.1117	-0.0033	0.1084
14	30	Unbiased-30krad	-0.0165	0.0138	0.0303
15	30	Unbiased-30krad	-0.0227	0.0357	0.0584
16	35	Biased-30krad	0.0007	0.017	0.0163
17	35	Biased-30krad	-0.0617	0.0326	0.0943
18	35	Biased-30krad	-0.0134	0.0451	0.0585
19	35	Biased-30krad	-0.0477	0.0856	0.1333
20	35	Biased-30krad	-0.0508	0.017	0.0678
30	50	Unbiased-50krad	0.0022	0.0419	0.0397
31	50	Unbiased-50krad	-0.0446	-0.0064	0.0382
32	50	Unbiased-50krad	-0.0851	0.0263	0.1114
33	50	Unbiased-50krad	-0.0243	0.0575	0.0818
34	50	Unbiased-50krad	-0.0649	0.006	0.0709
40	55	Biased-50krad	-0.068	0.0669	0.1349
41	55	Biased-50krad	-0.0617	0.0809	0.1426
42	55	Biased-50krad	-0.0586	0.0419	0.1005
43	55	Biased-50krad	-0.1351	-0.033	0.1021
44	55	Biased-50krad	-0.0711	0.0263	0.0974
45	100	Unbiased-100krad	-0.0149	0.0263	0.0412
46	100	Unbiased-100krad	-0.0071	0.0092	0.0163
47	100	Unbiased-100krad	-0.1054	-0.0236	0.0818
48	100	Unbiased-100krad	-0.0259	0.0763	0.1022
49	100	Unbiased-100krad	-0.0337	0.0809	0.1146
50	105	Biased-100krad	-0.0165	-0.0189	-0.0024
51	105	Biased-100krad	-0.029	0.0513	0.0803
52	105	Biased-100krad	-0.0524	-0.0205	0.0319
53	105	Biased-100krad	-0.0758	-0.0033	0.0725
54	105	Biased-100krad	-0.1054	0.0232	0.1286

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0836	-0.050833	-0.0118	0.036308	-0.0377	-0.0038333	0.0373	0.038024	0.0007	0.047	0.0944	0.04686
30	-0.1117	-0.048	-0.0149	0.043221	-0.0111	0.01134	0.0357	0.018859	0.0038	0.05934	0.1084	0.043775
35	-0.0617	-0.03458	0.0007	0.026758	0.017	0.03946	0.0856	0.028358	0.0163	0.07404	0.1333	0.043407
50	-0.0851	-0.04334	0.0022	0.034083	-0.0064	0.02506	0.0575	0.025935	0.0382	0.0684	0.1114	0.030702
55	-0.1351	-0.0789	-0.0586	0.031804	-0.033	0.0366	0.0809	0.044325	0.0974	0.1155	0.1426	0.021465
100	-0.1054	-0.0374	-0.0071	0.039352	-0.0236	0.03382	0.0809	0.044668	0.0163	0.07122	0.1146	0.041446
105	-0.1054	-0.05582	-0.0165	0.035828	-0.0205	0.00636	0.0513	0.030643	-0.0024	0.06218	0.1286	0.049834

Device Test: 39.10 _EA|SourceCurrent/COMP2/7/7///90.9/634//0///@EA_SOURCE





Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

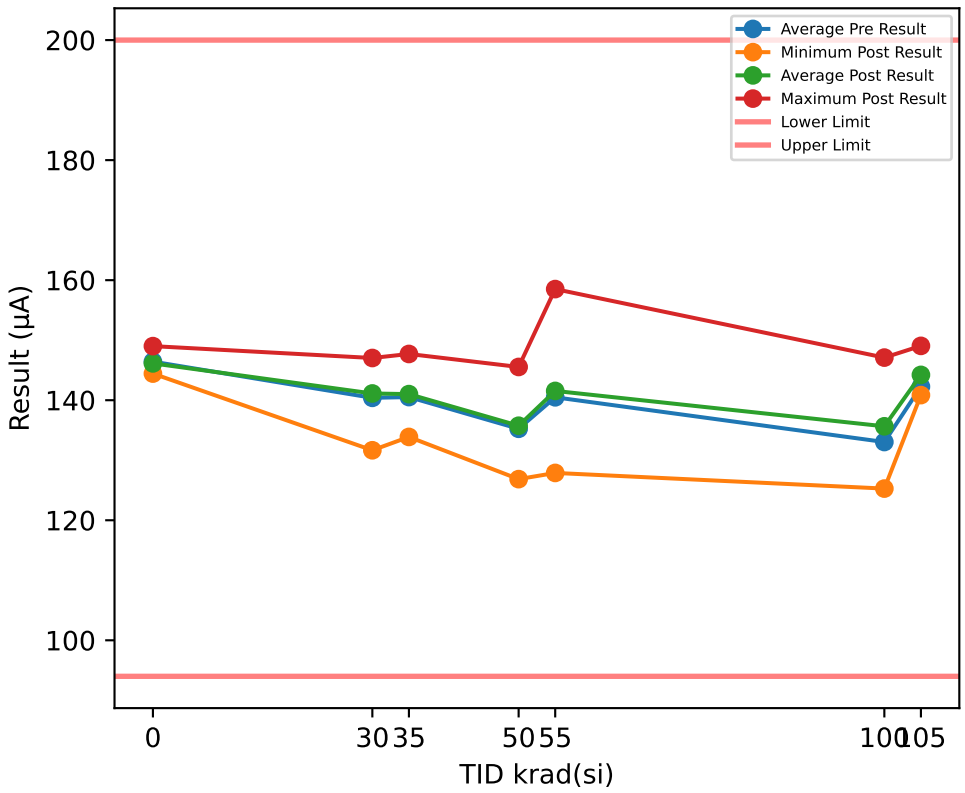
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	142.99	142.58	-0.412
2	0	CU2	130.87	130.53	-0.3316
3	0	CU3	141.55	141.17	-0.381
11	30	Unbiased-30krad	139.77	139.3	-0.468
12	30	Unbiased-30krad	145	143.64	-1.3596
13	30	Unbiased-30krad	149.06	151.9	2.8465
14	30	Unbiased-30krad	125	126.57	1.5714
15	30	Unbiased-30krad	135.44	135.58	0.1489
16	35	Biased-30krad	138.91	139.44	0.5332
17	35	Biased-30krad	147.74	148.13	0.3895
18	35	Biased-30krad	141.1	141.43	0.3313
19	35	Biased-30krad	146.98	147.22	0.2411
20	35	Biased-30krad	130.5	130.84	0.3307
30	50	Unbiased-50krad	130.21	131.91	1.7053
31	50	Unbiased-50krad	131.96	133.56	1.6031
32	50	Unbiased-50krad	131.88	133.99	2.1124
33	50	Unbiased-50krad	136.78	138.43	1.6491
34	50	Unbiased-50krad	146.09	148.08	1.9972
40	55	Biased-50krad	133.47	135.5	2.0213
41	55	Biased-50krad	144.74	144.37	-0.3629
42	55	Biased-50krad	144.57	145.73	1.1554
43	55	Biased-50krad	133.88	137.36	3.4832
44	55	Biased-50krad	125.42	125.62	0.2037
45	100	Unbiased-100krad	126.68	127.76	1.0825
46	100	Unbiased-100krad	132.14	134.09	1.9575
47	100	Unbiased-100krad	132.48	134.67	2.1931
48	100	Unbiased-100krad	138.98	141.89	2.9163
49	100	Unbiased-100krad	124.02	127.02	3
50	105	Biased-100krad	131.95	133.4	1.4541
51	105	Biased-100krad	116.32	117.95	1.6262
52	105	Biased-100krad	135.87	135.52	-0.3584
53	105	Biased-100krad	134.77	135.56	0.7941
54	105	Biased-100krad	146.22	146.54	0.3231

Test Statistics (µA)

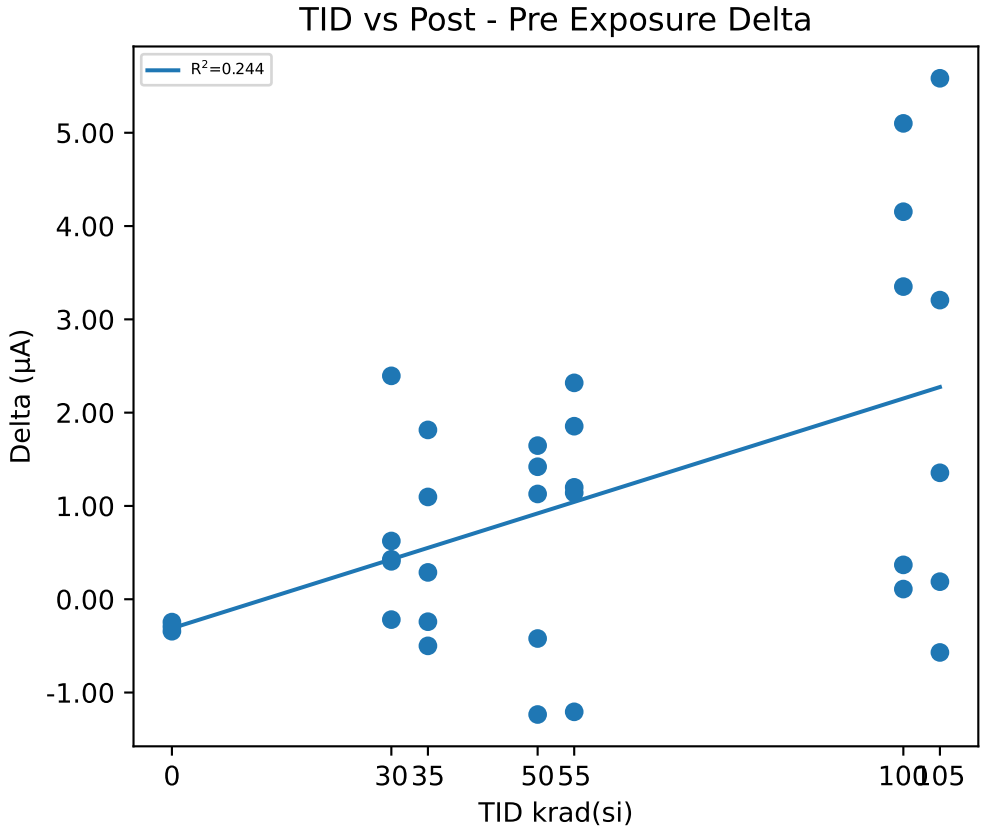
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	130.87	138.47	142.99	6.6239	130.53	138.1	142.58	6.585	-0.412	-0.37487	-0.3316	0.040549
30	125	138.85	149.06	9.307	126.57	139.4	151.9	9.4018	-1.3596	0.54784	2.8465	1.6704
35	130.5	141.05	147.74	6.9943	130.84	141.41	148.13	6.9748	0.2411	0.36516	0.5332	0.10788
50	130.21	135.38	146.09	6.4667	131.91	137.2	148.08	6.5464	1.6031	1.8134	2.1124	0.22699
55	125.42	136.42	144.74	8.2446	125.62	137.72	145.73	8.061	-0.3629	1.3001	3.4832	1.5227
100	124.02	130.86	138.98	5.7965	127.02	133.09	141.89	6.0465	1.0825	2.2299	3	0.78363
105	116.32	133.03	146.22	10.786	117.95	133.8	146.54	10.245	-0.3584	0.76782	1.6262	0.81772

Device Test: 39.11 _EA|SourceCurrent/COMP3/7/7///90.9/634//0///@EA_SOURCE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

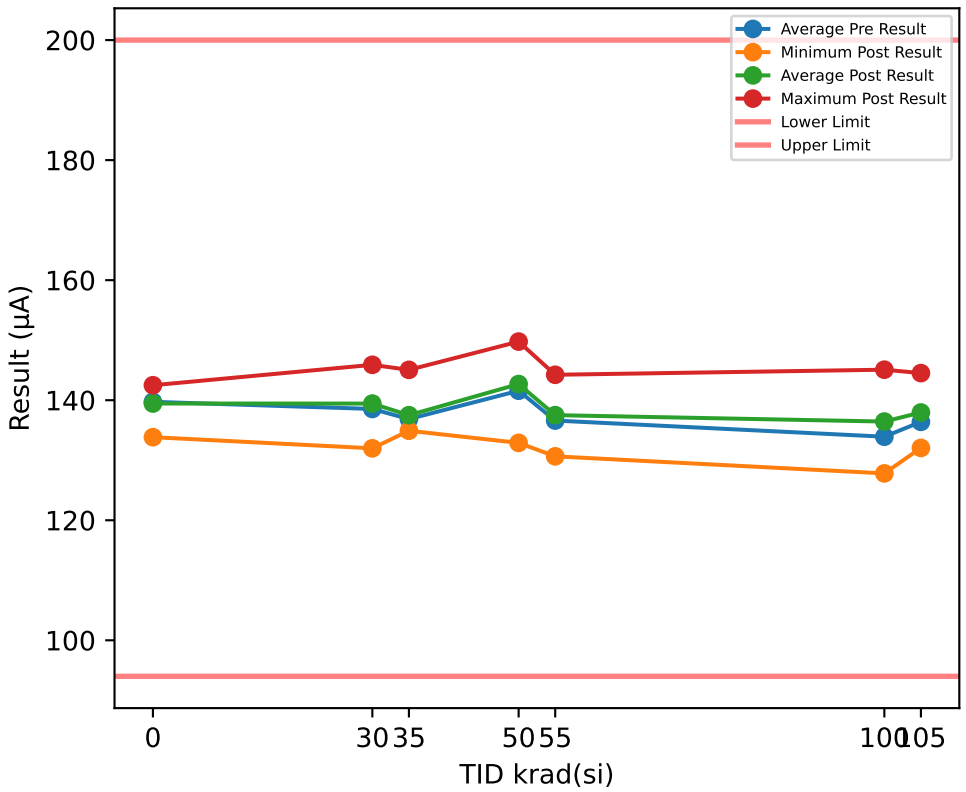
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	149.35	149.01	-0.343
2	0	CU2	144.73	144.44	-0.2935
3	0	CU3	145.2	144.96	-0.245
11	30	Unbiased-30krad	144.95	145.38	0.4283
12	30	Unbiased-30krad	138.77	139.18	0.4063
13	30	Unbiased-30krad	141.74	142.37	0.6244
14	30	Unbiased-30krad	129.26	131.66	2.3944
15	30	Unbiased-30krad	147.25	147.03	-0.2184
16	35	Biased-30krad	134.58	134.34	-0.2408
17	35	Biased-30krad	141.13	142.95	1.8149
18	35	Biased-30krad	146.61	147.7	1.0965
19	35	Biased-30krad	145.92	146.2	0.2877
20	35	Biased-30krad	134.38	133.88	-0.4997
30	50	Unbiased-50krad	125.2	126.85	1.6467
31	50	Unbiased-50krad	135.1	136.52	1.4202
32	50	Unbiased-50krad	134.27	133.03	-1.2355
33	50	Unbiased-50krad	135.67	136.8	1.1285
34	50	Unbiased-50krad	145.96	145.54	-0.421
40	55	Biased-50krad	148.74	150.6	1.8547
41	55	Biased-50krad	134.86	133.65	-1.2068
42	55	Biased-50krad	156.2	158.51	2.3193
43	55	Biased-50krad	126.74	127.88	1.1412
44	55	Biased-50krad	135.89	137.09	1.1995
45	100	Unbiased-100krad	129.77	130.14	0.3684
46	100	Unbiased-100krad	121.93	125.28	3.3512
47	100	Unbiased-100krad	135.95	136.06	0.1091
48	100	Unbiased-100krad	142	147.1	5.1005
49	100	Unbiased-100krad	135.53	139.68	4.1538
50	105	Biased-100krad	149.08	148.51	-0.5703
51	105	Biased-100krad	137.65	140.85	3.2063
52	105	Biased-100krad	141.34	141.53	0.1884
53	105	Biased-100krad	135.55	141.13	5.5839
54	105	Biased-100krad	147.7	149.05	1.3553

Test Statistics (µA)

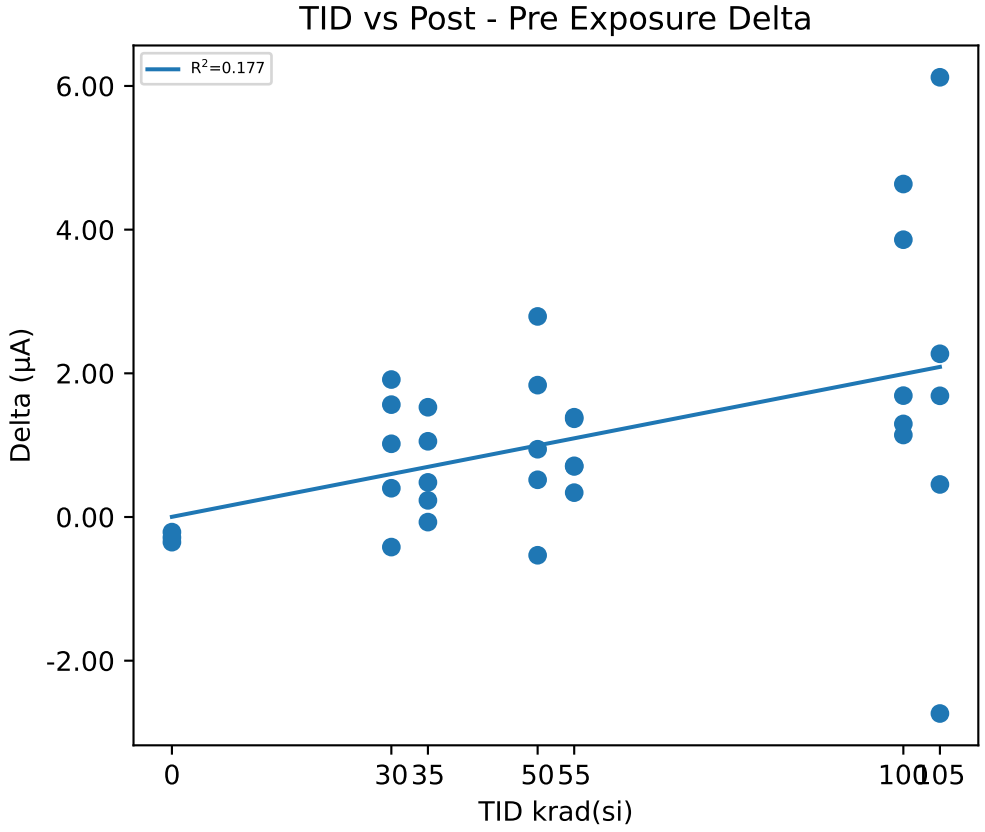
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	144.73	146.43	149.35	2.5438	144.44	146.14	149.01	2.5038	-0.343	-0.29383	-0.245	0.049001
30	129.26	140.4	147.25	7.0016	131.66	141.12	147.03	6.0812	-0.2184	0.727	2.3944	0.98445
35	134.38	140.52	146.61	5.9067	133.88	141.01	147.7	6.5364	-0.4997	0.49172	1.8149	0.95886
50	125.2	135.24	145.96	7.3621	126.85	135.75	145.54	6.7844	-1.2355	0.50778	1.6467	1.2666
55	126.74	140.49	156.2	11.797	127.88	141.55	158.51	12.637	-1.2068	1.0616	2.3193	1.3585
100	121.93	133.04	142	7.5688	125.28	135.65	147.1	8.448	0.1091	2.6166	5.1005	2.2591
105	135.55	142.26	149.08	5.9856	140.85	144.22	149.05	4.1802	-0.5703	1.9527	5.5839	2.4795

Device Test: 39.12 _EA|SourceCurrent/COMP4/7/7///90.9/634//0///@EA_SOURCE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



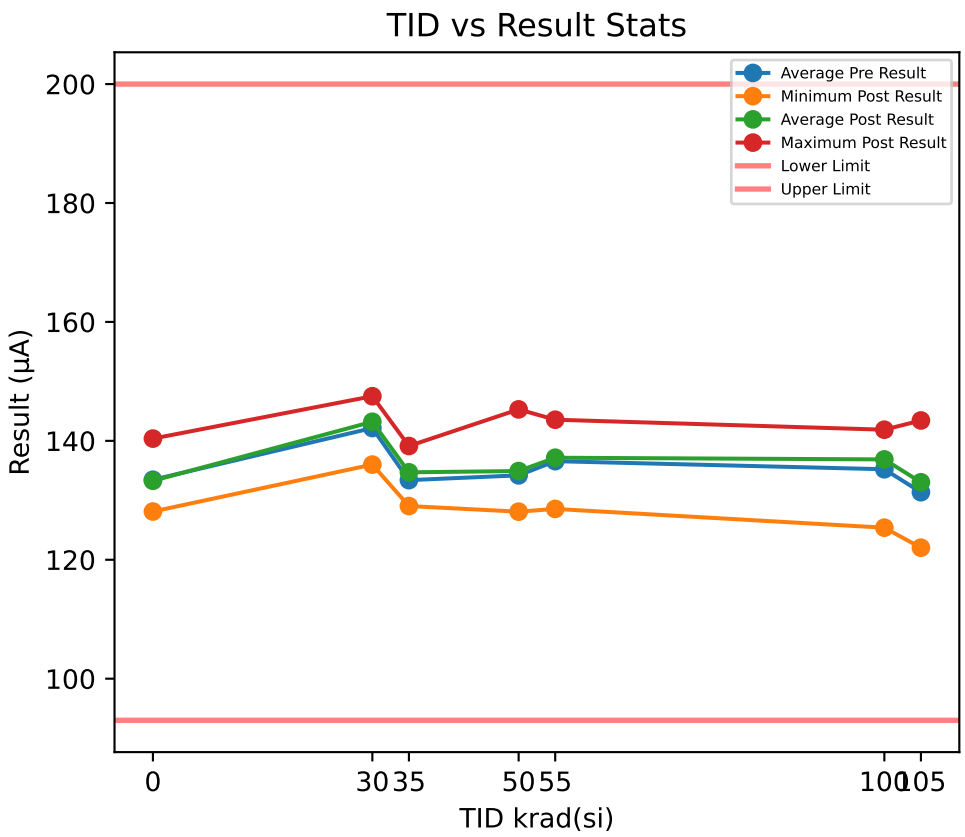
Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

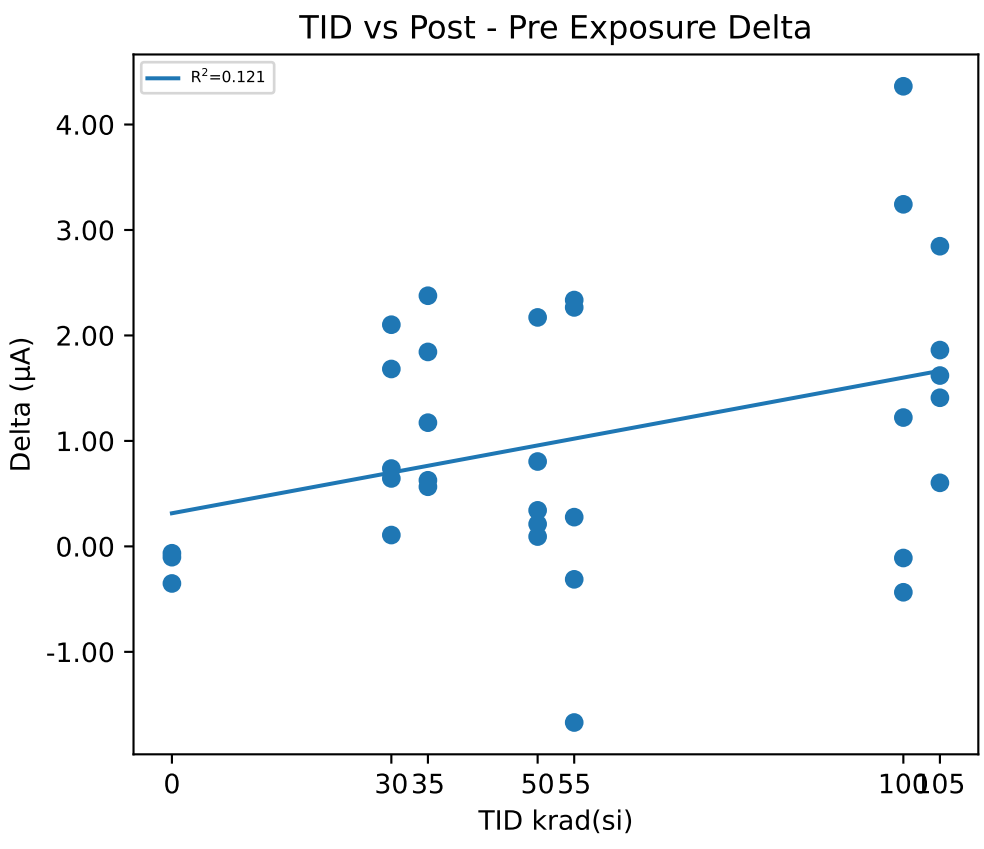
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	142.78	142.49	-0.2857
2	0	CU2	134.05	133.84	-0.2103
3	0	CU3	142.36	142.01	-0.3503
11	30	Unbiased-30krad	144.65	145.06	0.4004
12	30	Unbiased-30krad	146.31	145.9	-0.4186
13	30	Unbiased-30krad	135.91	137.83	1.9135
14	30	Unbiased-30krad	130.97	131.99	1.0192
15	30	Unbiased-30krad	134.87	136.43	1.5642
16	35	Biased-30krad	135.84	136.9	1.054
17	35	Biased-30krad	134.43	134.91	0.4821
18	35	Biased-30krad	135.2	135.12	-0.071
19	35	Biased-30krad	144.82	145.06	0.2317
20	35	Biased-30krad	133.98	135.51	1.5278
30	50	Unbiased-50krad	146.97	149.77	2.792
31	50	Unbiased-50krad	143.36	142.83	-0.5325
32	50	Unbiased-50krad	131.06	132.89	1.8355
33	50	Unbiased-50krad	141.86	142.37	0.5181
34	50	Unbiased-50krad	144.64	145.59	0.9434
40	55	Biased-50krad	129.26	130.65	1.389
41	55	Biased-50krad	142.13	142.46	0.3391
42	55	Biased-50krad	143.53	144.24	0.704
43	55	Biased-50krad	137.42	138.78	1.3672
44	55	Biased-50krad	130.72	131.44	0.7125
45	100	Unbiased-100krad	130.15	134.79	4.635
46	100	Unbiased-100krad	126.12	127.81	1.6896
47	100	Unbiased-100krad	136.37	137.51	1.1416
48	100	Unbiased-100krad	143.79	145.08	1.2958
49	100	Unbiased-100krad	133.17	137.03	3.86
50	105	Biased-100krad	137.85	135.12	-2.7352
51	105	Biased-100krad	129.78	132.05	2.2719
52	105	Biased-100krad	137.3	143.42	6.1207
53	105	Biased-100krad	134.21	134.66	0.4532
54	105	Biased-100krad	142.83	144.52	1.687

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	134.05	139.73	142.78	4.9237	133.84	139.45	142.49	4.8631	-0.3503	-0.2821	-0.2103	0.070069
30	130.97	138.54	146.31	6.6251	131.99	139.44	145.9	5.9249	-0.4186	0.89574	1.9135	0.9315
35	133.98	136.86	144.82	4.5113	134.91	137.5	145.06	4.2937	-0.071	0.64492	1.5278	0.64355
50	131.06	141.58	146.97	6.1749	132.89	142.69	149.77	6.2172	-0.5325	1.1113	2.792	1.268
55	129.26	136.61	143.53	6.4746	130.65	137.51	144.24	6.2329	0.3391	0.90236	1.389	0.45977
100	126.12	133.92	143.79	6.6896	127.81	136.44	145.08	6.1943	1.1416	2.5244	4.635	1.6091
105	129.78	136.39	142.83	4.8195	132.05	137.95	144.52	5.6276	-2.7352	1.5595	6.1207	3.2014

Device Test: 39.13 _EA|SinkCurrent/COMP1/7/7///90.9/634//0///@EA_SINK





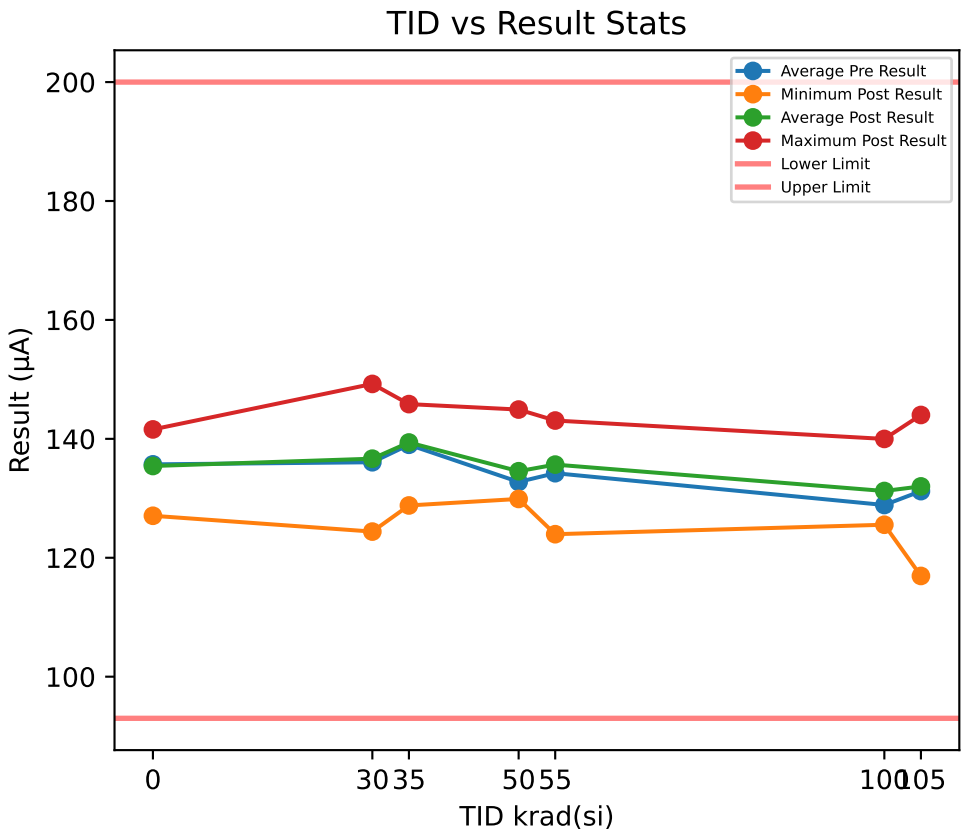
Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

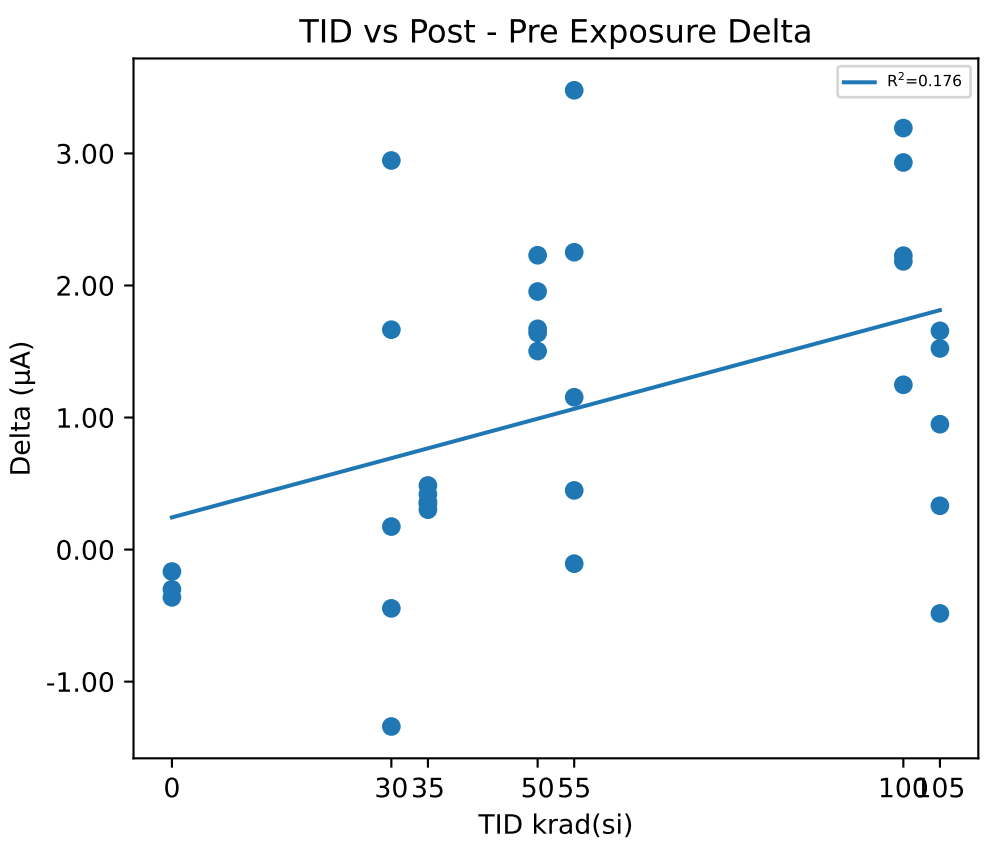
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	140.73	140.38	-0.3515
2	0	CU2	131.46	131.36	-0.1024
3	0	CU3	128.18	128.11	-0.0651
11	30	Unbiased-30krad	133.91	136.01	2.1019
12	30	Unbiased-30krad	145.64	146.29	0.6442
13	30	Unbiased-30krad	145.82	147.5	1.6821
14	30	Unbiased-30krad	140.11	140.21	0.1075
15	30	Unbiased-30krad	145.3	146.04	0.738
16	35	Biased-30krad	127.19	129.03	1.8438
17	35	Biased-30krad	136.75	139.13	2.3766
18	35	Biased-30krad	133.99	135.17	1.173
19	35	Biased-30krad	136.23	136.8	0.5654
20	35	Biased-30krad	132.78	133.41	0.6268
30	50	Unbiased-50krad	130.57	130.78	0.2118
31	50	Unbiased-50krad	135.74	136.54	0.8047
32	50	Unbiased-50krad	133.56	133.9	0.3417
33	50	Unbiased-50krad	127.99	128.09	0.0931
34	50	Unbiased-50krad	143.12	145.29	2.171
40	55	Biased-50krad	143.87	143.56	-0.3124
41	55	Biased-50krad	128.27	128.55	0.2773
42	55	Biased-50krad	145.11	143.44	-1.6699
43	55	Biased-50krad	134.61	136.94	2.3357
44	55	Biased-50krad	131.05	133.31	2.2658
45	100	Unbiased-100krad	137.51	141.87	4.3625
46	100	Unbiased-100krad	125.5	125.39	-0.1101
47	100	Unbiased-100krad	136.18	139.42	3.2433
48	100	Unbiased-100krad	138.57	139.79	1.2216
49	100	Unbiased-100krad	138.36	137.92	-0.4351
50	105	Biased-100krad	138.46	140.08	1.6199
51	105	Biased-100krad	127.14	129.99	2.8461
52	105	Biased-100krad	127.78	129.64	1.8614
53	105	Biased-100krad	121.43	122.03	0.6027
54	105	Biased-100krad	142.02	143.43	1.4093

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	128.18	133.45	140.73	6.51	128.11	133.28	140.38	6.3557	-0.3515	-0.173	-0.0651	0.15571
30	133.91	142.15	145.82	5.1903	136.01	143.21	147.5	4.9184	0.1075	1.0547	2.1019	0.8149
35	127.19	133.39	136.75	3.8269	129.03	134.71	139.13	3.8089	0.5654	1.3171	2.3766	0.78458
50	127.99	134.2	143.12	5.7884	128.09	134.92	145.29	6.615	0.0931	0.72446	2.171	0.85248
55	128.27	136.58	145.11	7.5715	128.55	137.16	143.56	6.5049	-1.6699	0.5793	2.3357	1.723
100	125.5	135.22	138.57	5.5134	125.39	136.88	141.87	6.5735	-0.4351	1.6564	4.3625	2.0932
105	121.43	131.36	142.02	8.5625	122.03	133.03	143.43	8.6536	0.6027	1.6679	2.8461	0.81078

Device Test: 39.14 _EA|SinkCurrent/COMP2/7/7///90.9/634//0///@EA_SINK





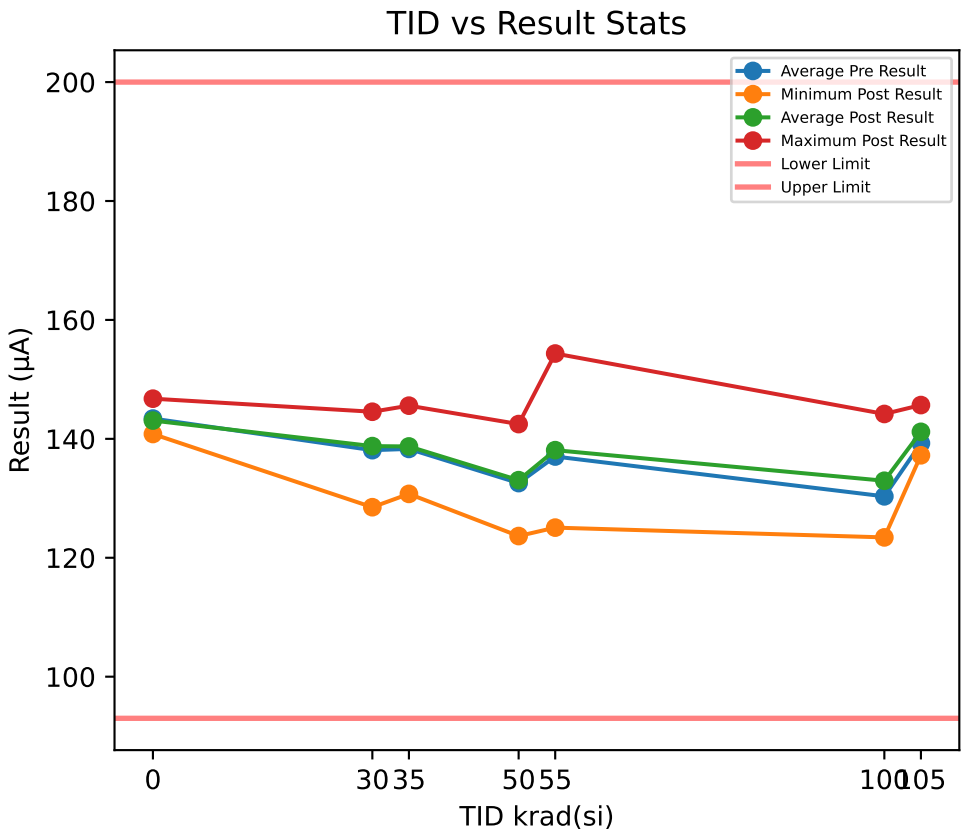
Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

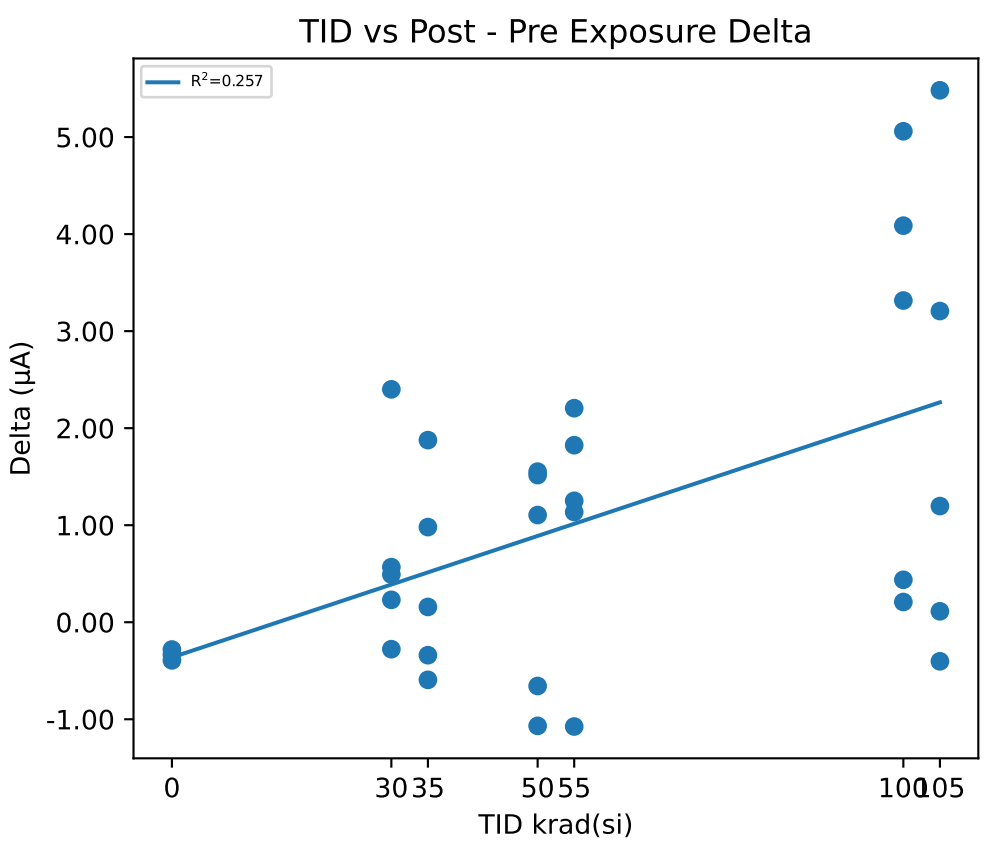
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	141.89	141.59	-0.3008
2	0	CU2	127.23	127.06	-0.1661
3	0	CU3	138.01	137.65	-0.3618
11	30	Unbiased-30krad	137.21	136.76	-0.4452
12	30	Unbiased-30krad	141.72	140.38	-1.3398
13	30	Unbiased-30krad	146.29	149.24	2.9467
14	30	Unbiased-30krad	122.74	124.4	1.6652
15	30	Unbiased-30krad	132.36	132.53	0.1743
16	35	Biased-30krad	137.48	137.9	0.4197
17	35	Biased-30krad	144.73	145.22	0.4855
18	35	Biased-30krad	138.82	139.18	0.3618
19	35	Biased-30krad	145.54	145.84	0.3022
20	35	Biased-30krad	128.45	128.8	0.3454
30	50	Unbiased-50krad	128.22	129.89	1.6719
31	50	Unbiased-50krad	129.53	131.17	1.6404
32	50	Unbiased-50krad	128.94	131.17	2.2289
33	50	Unbiased-50krad	134.11	135.61	1.5033
34	50	Unbiased-50krad	142.97	144.93	1.9543
40	55	Biased-50krad	131.4	133.65	2.2518
41	55	Biased-50krad	142.26	142.15	-0.1067
42	55	Biased-50krad	141.93	143.08	1.1536
43	55	Biased-50krad	132.01	135.49	3.4782
44	55	Biased-50krad	123.51	123.96	0.4483
45	100	Unbiased-100krad	124.31	125.55	1.248
46	100	Unbiased-100krad	130.19	132.41	2.2259
47	100	Unbiased-100krad	130.31	132.49	2.1826
48	100	Unbiased-100krad	137.05	139.99	2.9315
49	100	Unbiased-100krad	122.51	125.7	3.1922
50	105	Biased-100krad	130.25	131.77	1.5232
51	105	Biased-100krad	115.28	116.94	1.6566
52	105	Biased-100krad	133.88	133.39	-0.4833
53	105	Biased-100krad	132.95	133.9	0.9494
54	105	Biased-100krad	143.68	144.01	0.3318

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	127.23	135.71	141.89	7.5959	127.06	135.43	141.59	7.5117	-0.3618	-0.27623	-0.1661	0.10014
30	122.74	136.06	146.29	9.0725	124.4	136.66	149.24	9.2104	-1.3398	0.60024	2.9467	1.7087
35	128.45	139	145.54	6.8781	128.8	139.39	145.84	6.8931	0.3022	0.38292	0.4855	0.071142
50	128.22	132.75	142.97	6.1597	129.89	134.55	144.93	6.1922	1.5033	1.7998	2.2289	0.29055
55	123.51	134.22	142.26	7.929	123.96	135.67	143.08	7.7154	-0.1067	1.445	3.4782	1.438
100	122.51	128.87	137.05	5.7471	125.55	131.23	139.99	5.9681	1.248	2.356	3.1922	0.75913
105	115.28	131.21	143.68	10.25	116.94	132	144.01	9.7041	-0.4833	0.79554	1.6566	0.88672

Device Test: 39.15 _EA|SinkCurrent/COMP3/7/7///90.9/634//0///@EA_SINK





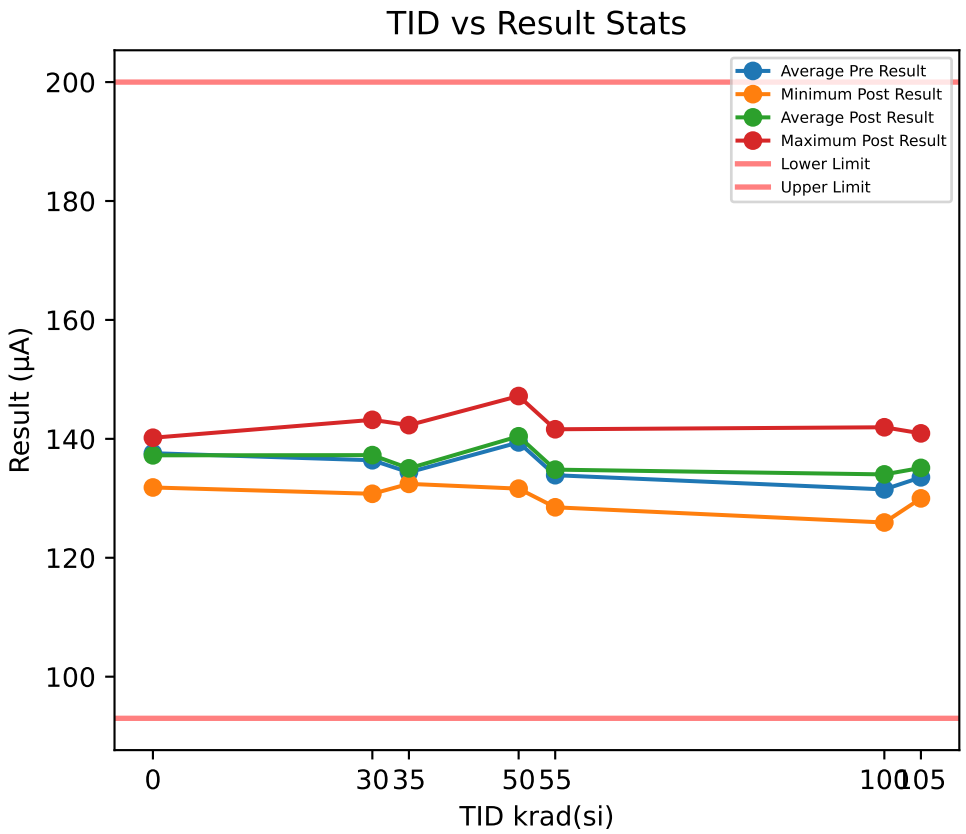
Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

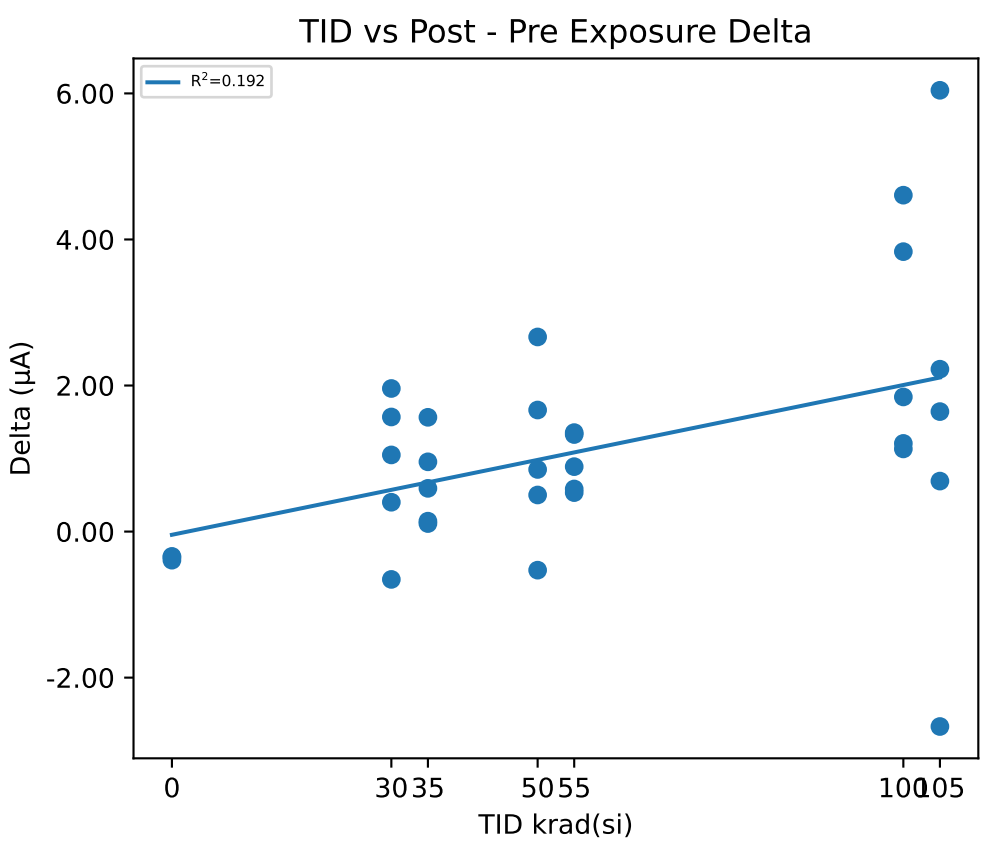
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	147.15	146.76	-0.3933
2	0	CU2	141.1	140.82	-0.2813
3	0	CU3	141.99	141.66	-0.3333
11	30	Unbiased-30krad	142.43	142.92	0.4918
12	30	Unbiased-30krad	137.79	138.02	0.2307
13	30	Unbiased-30krad	139.32	139.89	0.5678
14	30	Unbiased-30krad	126.1	128.5	2.4001
15	30	Unbiased-30krad	144.84	144.56	-0.2779
16	35	Biased-30krad	132.54	132.2	-0.34
17	35	Biased-30krad	138.96	140.84	1.8767
18	35	Biased-30krad	144.6	145.58	0.9805
19	35	Biased-30krad	144.09	144.25	0.1575
20	35	Biased-30krad	131.34	130.74	-0.5938
30	50	Unbiased-50krad	122.1	123.65	1.5517
31	50	Unbiased-50krad	133.06	134.57	1.5164
32	50	Unbiased-50krad	131.59	130.52	-1.0681
33	50	Unbiased-50krad	132.92	134.02	1.1048
34	50	Unbiased-50krad	143.14	142.48	-0.6573
40	55	Biased-50krad	145.48	147.31	1.8246
41	55	Biased-50krad	131.26	130.18	-1.0747
42	55	Biased-50krad	152.14	154.35	2.2057
43	55	Biased-50krad	123.93	125.07	1.1358
44	55	Biased-50krad	132.32	133.57	1.2511
45	100	Unbiased-100krad	127.26	127.7	0.4372
46	100	Unbiased-100krad	120.11	123.43	3.3155
47	100	Unbiased-100krad	132.92	133.13	0.2085
48	100	Unbiased-100krad	139.12	144.18	5.0596
49	100	Unbiased-100krad	132.23	136.31	4.087
50	105	Biased-100krad	145.18	144.78	-0.4028
51	105	Biased-100krad	135.25	138.46	3.2069
52	105	Biased-100krad	139.63	139.74	0.1126
53	105	Biased-100krad	131.75	137.24	5.4821
54	105	Biased-100krad	144.48	145.68	1.197

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	141.1	143.41	147.15	3.2668	140.82	143.08	146.76	3.2141	-0.3933	-0.33597	-0.2813	0.056048
30	126.1	138.1	144.84	7.2396	128.5	138.78	144.56	6.2843	-0.2779	0.6825	2.4001	1.0156
35	131.34	138.31	144.6	6.2317	130.74	138.72	145.58	6.8604	-0.5938	0.41618	1.8767	1.0137
50	122.1	132.56	143.14	7.4613	123.65	133.05	142.48	6.837	-1.0681	0.4895	1.5517	1.2553
55	123.93	137.03	152.14	11.477	125.07	138.1	154.35	12.266	-1.0747	1.0685	2.2057	1.2744
100	120.11	130.33	139.12	7.0976	123.43	132.95	144.18	7.9968	0.2085	2.6216	5.0596	2.189
105	131.75	139.26	145.18	5.8075	137.24	141.18	145.68	3.8162	-0.4028	1.9192	5.4821	2.4254

Device Test: 39.16 _EA|SinkCurrent/COMP4/7/7///90.9/634//0///@EA_SINK





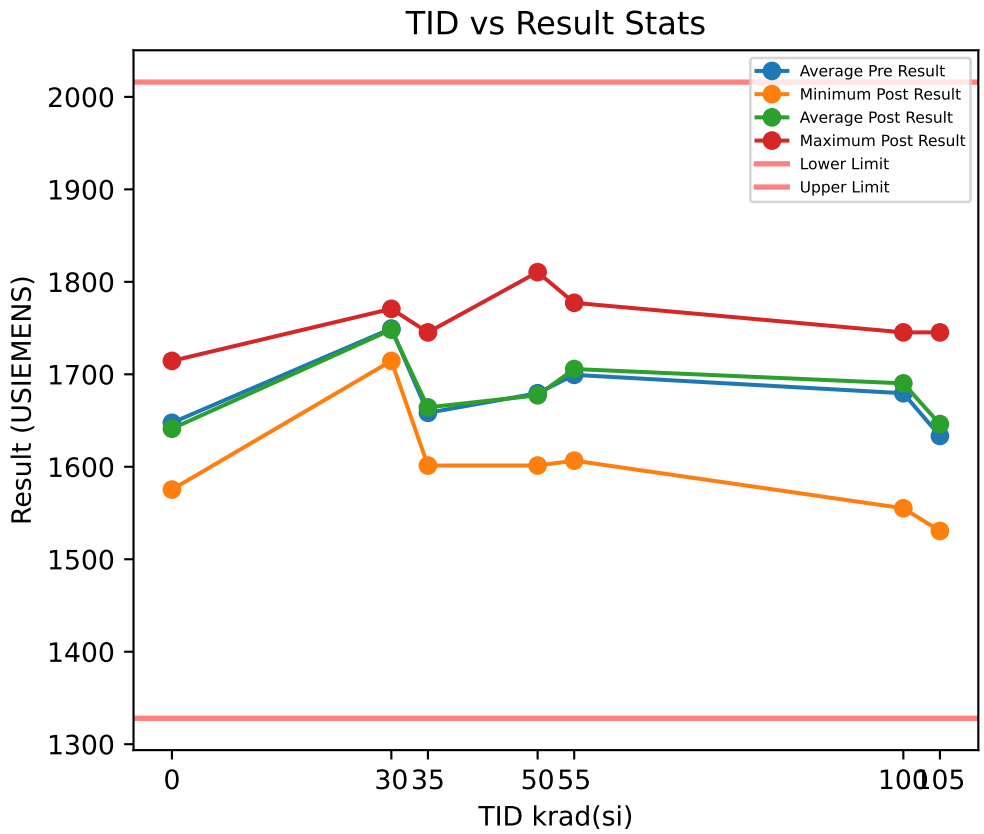
Test Results (Lower Limit = 93.0, Upper Limit = 200.0 (µA))

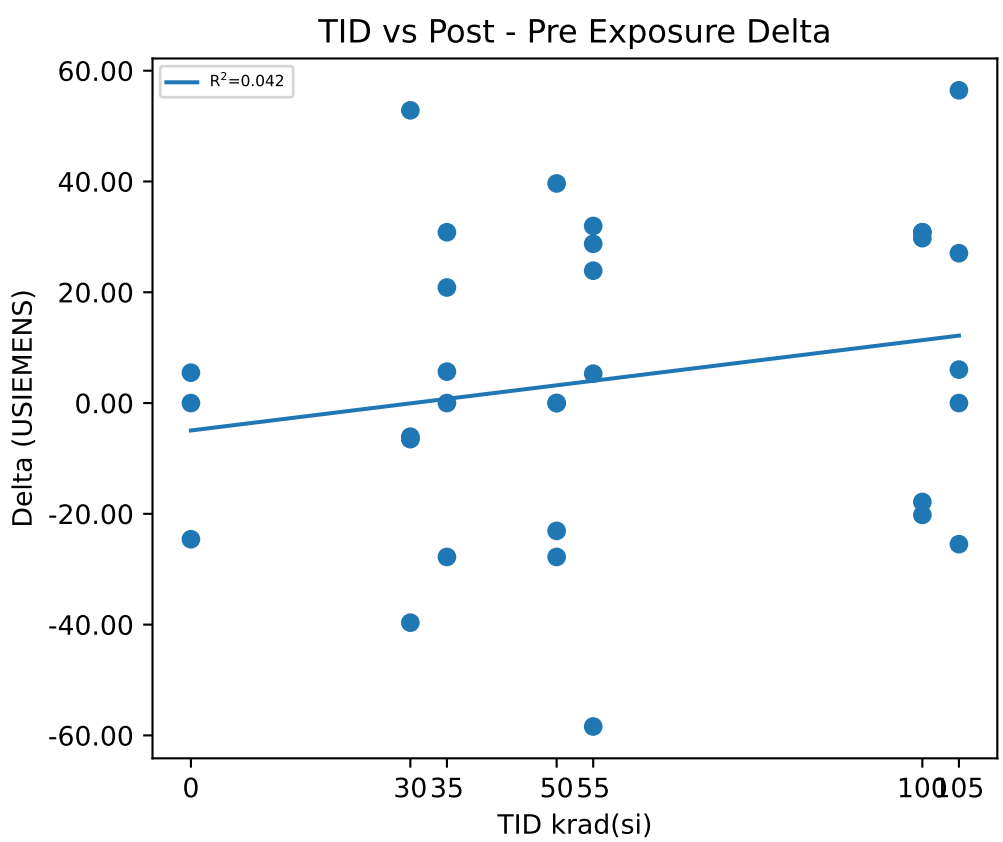
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	140.53	140.19	-0.3398
2	0	CU2	132.17	131.82	-0.3513
3	0	CU3	140.06	139.67	-0.3917
11	30	Unbiased-30krad	142.79	143.2	0.4018
12	30	Unbiased-30krad	143.45	142.8	-0.655
13	30	Unbiased-30krad	133.03	134.99	1.9594
14	30	Unbiased-30krad	129.71	130.76	1.0496
15	30	Unbiased-30krad	133	134.57	1.5693
16	35	Biased-30krad	133.95	134.9	0.9552
17	35	Biased-30krad	132	132.59	0.592
18	35	Biased-30krad	132.32	132.43	0.1099
19	35	Biased-30krad	142.16	142.31	0.1425
20	35	Biased-30krad	131.4	132.97	1.5648
30	50	Unbiased-50krad	144.53	147.2	2.665
31	50	Unbiased-50krad	140.6	140.07	-0.5284
32	50	Unbiased-50krad	129.96	131.63	1.6647
33	50	Unbiased-50krad	139.91	140.41	0.5011
34	50	Unbiased-50krad	142	142.85	0.8506
40	55	Biased-50krad	127.68	129.01	1.3288
41	55	Biased-50krad	138.24	138.82	0.5834
42	55	Biased-50krad	141.08	141.61	0.5335
43	55	Biased-50krad	134.82	136.18	1.3554
44	55	Biased-50krad	127.6	128.49	0.8891
45	100	Unbiased-100krad	127.15	131.75	4.6065
46	100	Unbiased-100krad	124.09	125.93	1.8437
47	100	Unbiased-100krad	134.95	136.09	1.1318
48	100	Unbiased-100krad	140.74	141.95	1.2073
49	100	Unbiased-100krad	130.56	134.39	3.8333
50	105	Biased-100krad	135.18	132.51	-2.6693
51	105	Biased-100krad	127.76	129.99	2.2235
52	105	Biased-100krad	134.88	140.92	6.0428
53	105	Biased-100krad	130.56	131.25	0.6913
54	105	Biased-100krad	139.25	140.9	1.643

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	132.17	137.59	140.53	4.6939	131.82	137.23	140.19	4.6869	-0.3917	-0.36093	-0.3398	0.027258
30	129.71	136.4	143.45	6.2916	130.76	137.26	143.2	5.4905	-0.655	0.86502	1.9594	1.0311
35	131.4	134.37	142.16	4.4592	132.43	135.04	142.31	4.1808	0.1099	0.67288	1.5648	0.60828
50	129.96	139.4	144.53	5.565	131.63	140.43	147.2	5.6856	-0.5284	1.0306	2.665	1.2059
55	127.6	133.88	141.08	6.1143	128.49	134.82	141.61	5.8695	0.5335	0.93804	1.3554	0.39329
100	124.09	131.5	140.74	6.5587	125.93	134.02	141.95	5.8694	1.1318	2.5245	4.6065	1.5958
105	127.76	133.53	139.25	4.455	129.99	135.11	140.92	5.3652	-2.6693	1.5863	6.0428	3.1297

Device Test: 39.17 _EA|Transconductance/VSNS1/7/7///90.9/634//0///@EA_GM_25C





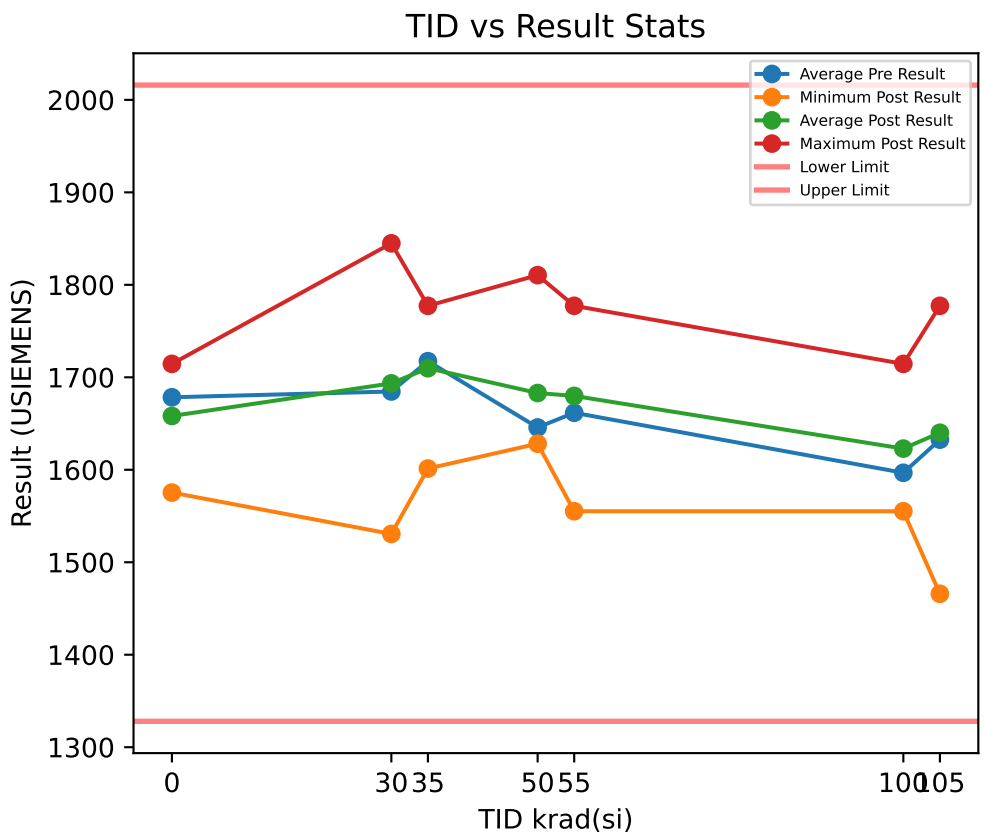
Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

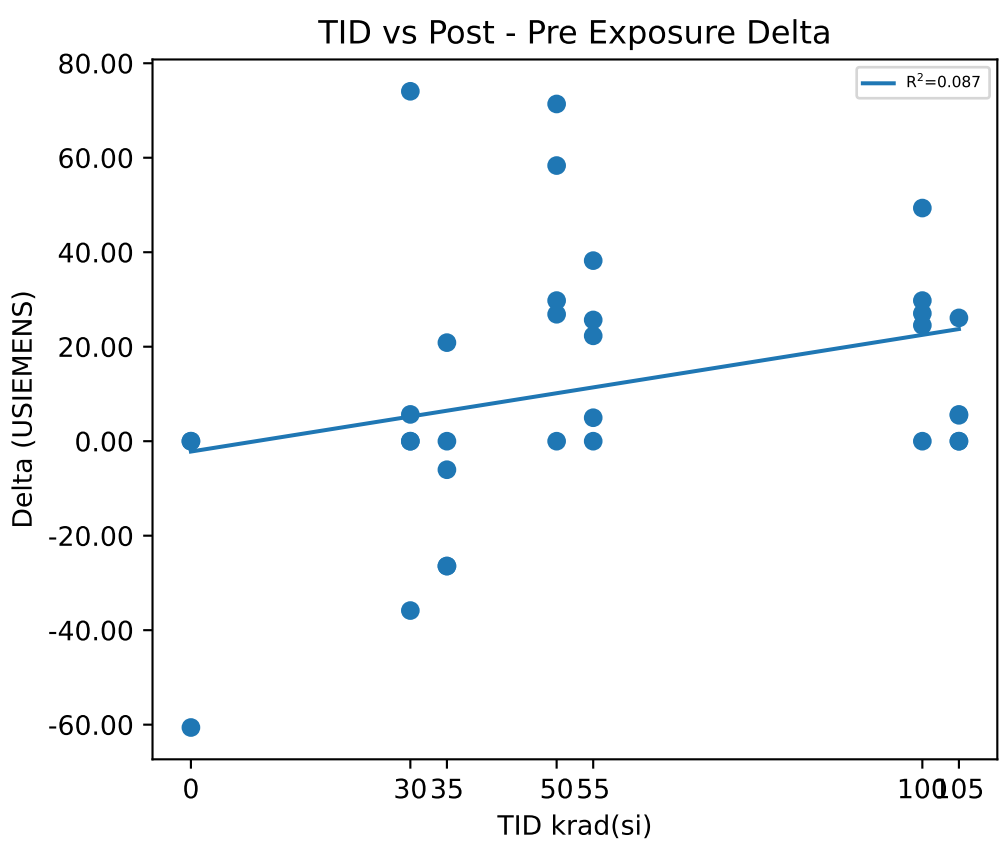
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1739.1	1714.5	-24.581
2	0	CU2	1628.2	1633.7	5.4821
3	0	CU3	1575.3	1575.3	0
11	30	Unbiased-30krad	1661.7	1714.5	52.844
12	30	Unbiased-30krad	1777.3	1770.8	-6.4865
13	30	Unbiased-30krad	1810.5	1770.8	-39.645
14	30	Unbiased-30krad	1720.6	1714.5	-6.0798
15	30	Unbiased-30krad	1777.3	1770.8	-6.4865
16	35	Biased-30krad	1580.5	1601.3	20.864
17	35	Biased-30krad	1714.5	1745.3	30.836
18	35	Biased-30krad	1656	1661.7	5.6712
19	35	Biased-30krad	1684.7	1684.7	0
20	35	Biased-30krad	1656	1628.2	-27.785
30	50	Unbiased-50krad	1656	1628.2	-27.785
31	50	Unbiased-50krad	1684.7	1684.7	0
32	50	Unbiased-50krad	1684.7	1661.7	-23.079
33	50	Unbiased-50krad	1601.3	1601.3	0
34	50	Unbiased-50krad	1770.8	1810.5	39.645
40	55	Biased-50krad	1745.3	1777.3	31.966
41	55	Biased-50krad	1601.3	1606.6	5.3024
42	55	Biased-50krad	1803.7	1745.3	-58.394
43	55	Biased-50krad	1690.6	1714.5	23.895
44	55	Biased-50krad	1656	1684.7	28.75
45	100	Unbiased-100krad	1714.5	1745.3	30.836
46	100	Unbiased-100krad	1575.3	1555.1	-20.197
47	100	Unbiased-100krad	1684.7	1714.5	29.766
48	100	Unbiased-100krad	1714.5	1745.3	30.836
49	100	Unbiased-100krad	1708.5	1690.6	-17.858
50	105	Biased-100krad	1708.5	1714.5	6.037
51	105	Biased-100krad	1550.2	1606.6	56.463
52	105	Biased-100krad	1606.6	1633.7	27.048
53	105	Biased-100krad	1530.6	1530.6	0
54	105	Biased-100krad	1770.8	1745.3	-25.479

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1647.5	1739.1	83.568	1575.3	1641.2	1714.5	69.884	-24.581	-6.3662	5.4821	16.011
30	1661.7	1749.5	1810.5	58.769	1714.5	1748.3	1770.8	30.845	-39.645	-1.1707	52.844	33.461
35	1580.5	1658.3	1714.5	49.814	1601.3	1664.3	1745.3	55.362	-27.785	5.9174	30.836	22.446
50	1601.3	1679.5	1770.8	61.353	1601.3	1677.3	1810.5	80.954	-27.785	-2.2437	39.645	26.698
55	1601.3	1699.4	1803.7	78.382	1606.6	1705.7	1777.3	65.248	-58.394	6.3039	31.966	37.612
100	1575.3	1679.5	1714.5	59.511	1555.1	1690.2	1745.3	78.918	-20.197	10.677	30.836	27.132
105	1530.6	1633.3	1770.8	103.35	1530.6	1646.2	1745.3	85.989	-25.479	12.814	56.463	30.759

Device Test: 39.18 _EA|Transconductance/VSNS2/7/7///90.9/634//0///@EA_GM_25C





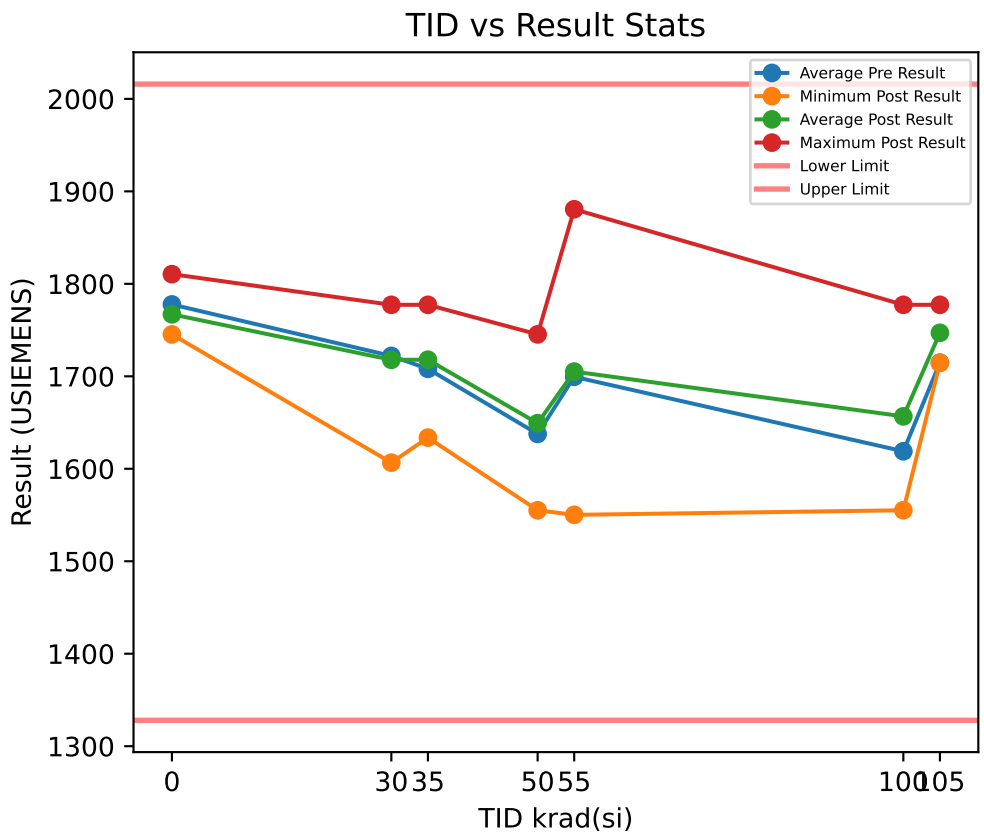
Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

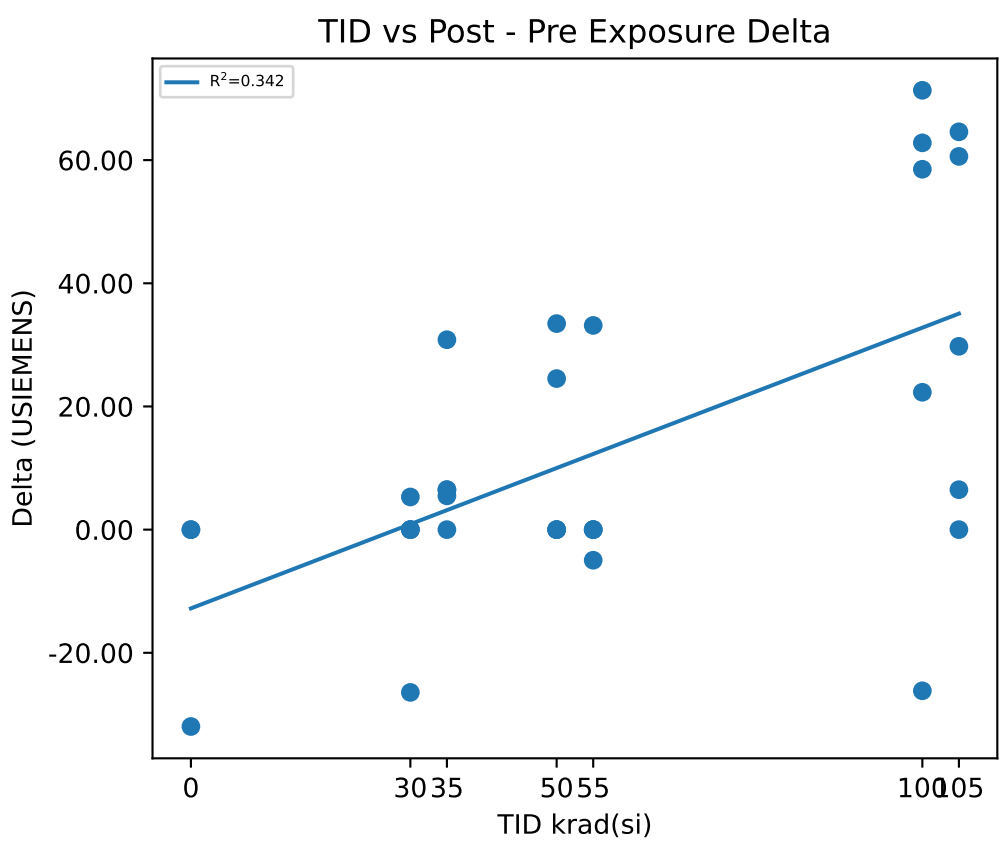
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1714.5	1714.5	0
2	0	CU2	1575.3	1575.3	0
3	0	CU3	1745.3	1684.7	-60.602
11	30	Unbiased-30krad	1720.6	1684.7	-35.845
12	30	Unbiased-30krad	1745.3	1745.3	0
13	30	Unbiased-30krad	1770.8	1844.9	74.065
14	30	Unbiased-30krad	1530.6	1530.6	0
15	30	Unbiased-30krad	1656	1661.7	5.6712
16	35	Biased-30krad	1684.7	1684.7	0
17	35	Biased-30krad	1803.7	1777.3	-26.428
18	35	Biased-30krad	1714.5	1708.5	-6.037
19	35	Biased-30krad	1803.7	1777.3	-26.428
20	35	Biased-30krad	1580.5	1601.3	20.864
30	50	Unbiased-50krad	1575.3	1633.7	58.346
31	50	Unbiased-50krad	1601.3	1628.2	26.868
32	50	Unbiased-50krad	1628.2	1628.2	0
33	50	Unbiased-50krad	1684.7	1714.5	29.766
34	50	Unbiased-50krad	1739.1	1810.5	71.38
40	55	Biased-50krad	1633.7	1633.7	0
41	55	Biased-50krad	1739.1	1777.3	38.222
42	55	Biased-50krad	1751.6	1777.3	25.665
43	55	Biased-50krad	1633.7	1656	22.303
44	55	Biased-50krad	1550.2	1555.1	4.9685
45	100	Unbiased-100krad	1555.1	1555.1	0
46	100	Unbiased-100krad	1606.6	1633.7	27.048
47	100	Unbiased-100krad	1606.6	1656	49.351
48	100	Unbiased-100krad	1684.7	1714.5	29.766
49	100	Unbiased-100krad	1530.6	1555.1	24.529
50	105	Biased-100krad	1628.2	1633.7	5.4821
51	105	Biased-100krad	1439.8	1465.9	26.099
52	105	Biased-100krad	1661.7	1661.7	0
53	105	Biased-100krad	1656	1661.7	5.6712
54	105	Biased-100krad	1777.3	1777.3	0

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1678.4	1745.3	90.57	1575.3	1658.2	1714.5	73.281	-60.602	-20.201	0	34.989
30	1530.6	1684.7	1770.8	96.11	1530.6	1693.4	1844.9	115.36	-35.845	8.7781	74.065	40.054
35	1580.5	1717.4	1803.7	93.183	1601.3	1709.8	1777.3	73.329	-26.428	-7.6059	20.864	19.871
50	1575.3	1645.7	1739.1	66.086	1628.2	1683	1810.5	80.12	0	37.272	71.38	28.113
55	1550.2	1661.7	1751.6	83.793	1555.1	1679.9	1777.3	96.499	0	18.232	38.222	15.65
100	1530.6	1596.8	1684.7	59.251	1555.1	1622.9	1714.5	68.528	0	26.139	49.351	17.597
105	1439.8	1632.6	1777.3	122	1465.9	1640	1777.3	111.97	0	7.4504	26.099	10.791

Device Test: 39.19 _EA|Transconductance/VSNS3/7/7///90.9/634//0///@EA_GM_25C





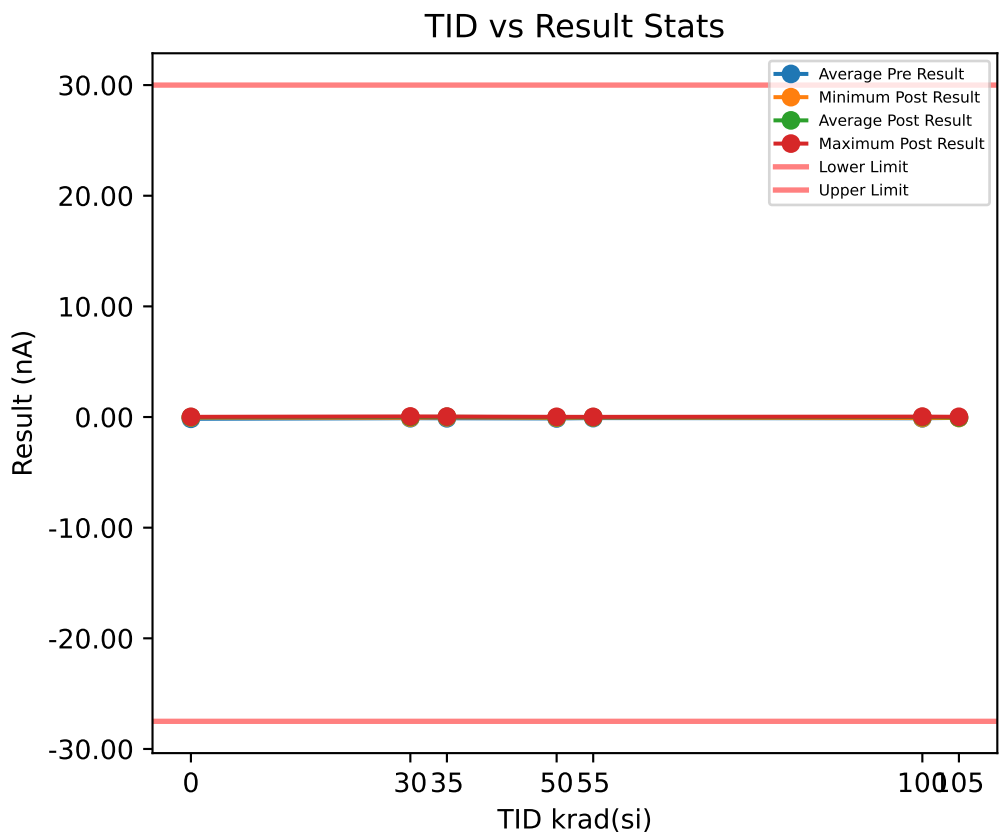
Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

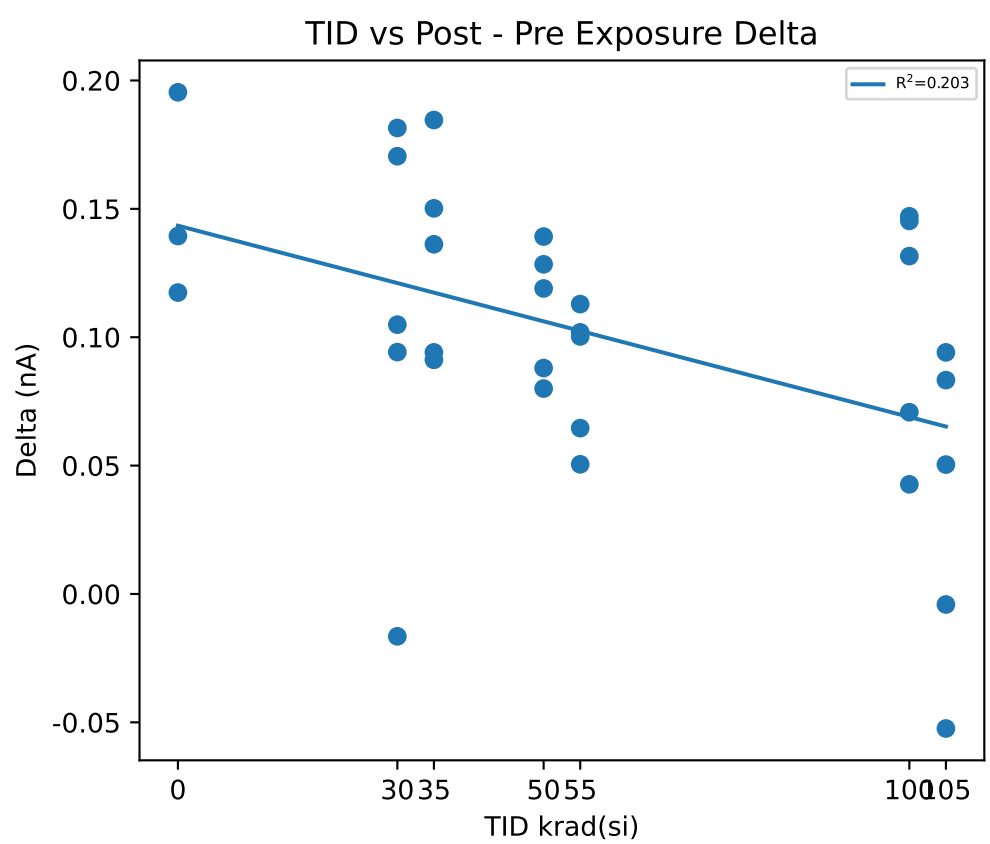
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1810.5	1810.5	0
2	0	CU2	1745.3	1745.3	0
3	0	CU3	1777.3	1745.3	-31.966
11	30	Unbiased-30krad	1745.3	1745.3	0
12	30	Unbiased-30krad	1714.5	1714.5	0
13	30	Unbiased-30krad	1745.3	1745.3	0
14	30	Unbiased-30krad	1601.3	1606.6	5.3024
15	30	Unbiased-30krad	1803.7	1777.3	-26.428
16	35	Biased-30krad	1656	1656	0
17	35	Biased-30krad	1714.5	1745.3	30.836
18	35	Biased-30krad	1770.8	1777.3	6.4865
19	35	Biased-30krad	1770.8	1777.3	6.4865
20	35	Biased-30krad	1628.2	1633.7	5.4821
30	50	Unbiased-50krad	1530.6	1555.1	24.529
31	50	Unbiased-50krad	1628.2	1661.7	33.456
32	50	Unbiased-50krad	1628.2	1628.2	0
33	50	Unbiased-50krad	1656	1656	0
34	50	Unbiased-50krad	1745.3	1745.3	0
40	55	Biased-50krad	1777.3	1810.5	33.159
41	55	Biased-50krad	1628.2	1628.2	0
42	55	Biased-50krad	1880.6	1880.6	0
43	55	Biased-50krad	1555.1	1550.2	-4.9685
44	55	Biased-50krad	1656	1656	0
45	100	Unbiased-100krad	1606.6	1580.5	-26.167
46	100	Unbiased-100krad	1483.8	1555.1	71.337
47	100	Unbiased-100krad	1633.7	1656	22.303
48	100	Unbiased-100krad	1714.5	1777.3	62.802
49	100	Unbiased-100krad	1656	1714.5	58.515
50	105	Biased-100krad	1777.3	1777.3	0
51	105	Biased-100krad	1684.7	1714.5	29.766
52	105	Biased-100krad	1684.7	1745.3	60.602
53	105	Biased-100krad	1656	1720.6	64.595
54	105	Biased-100krad	1770.8	1777.3	6.4865

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1745.3	1777.7	1810.5	32.564	1745.3	1767	1810.5	37.6	-31.966	-10.655	0	18.456
30	1601.3	1722.1	1803.7	74.81	1606.6	1717.8	1777.3	66.004	-26.428	-4.2252	5.3024	12.623
35	1628.2	1708.1	1770.8	65.207	1633.7	1717.9	1777.3	68.44	0	9.8583	30.836	12.033
50	1530.6	1637.7	1745.3	76.761	1555.1	1649.3	1745.3	68.432	0	11.597	33.456	16.191
55	1555.1	1699.5	1880.6	129.11	1550.2	1705.1	1880.6	136.24	-4.9685	5.638	33.159	15.534
100	1483.8	1618.9	1714.5	85.345	1555.1	1656.7	1777.3	92.212	-26.167	37.758	71.337	40.345
105	1656	1714.7	1777.3	55.478	1714.5	1747	1777.3	29.973	0	32.29	64.595	29.833

Device Test: 39.2 _EA|Leakage/VSNS2/7/7///90.9/634//0///@IVSNS_LKG





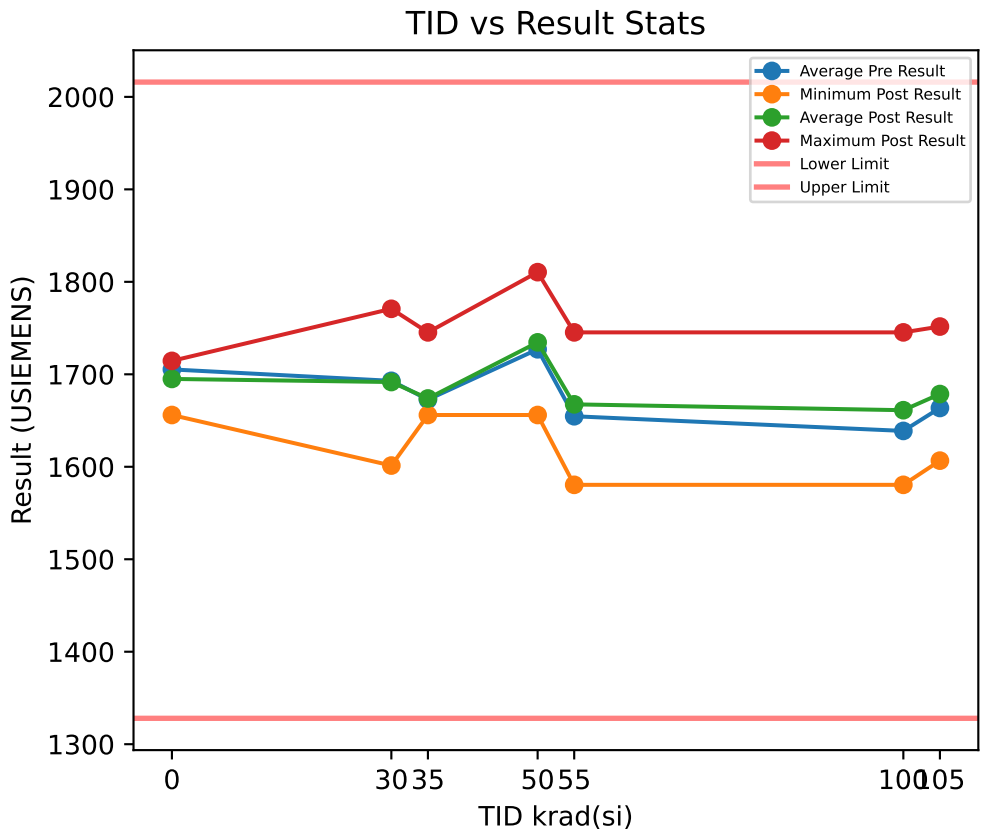
Test Results (Lower Limit = -27.5, Upper Limit = 30.0 (nA))

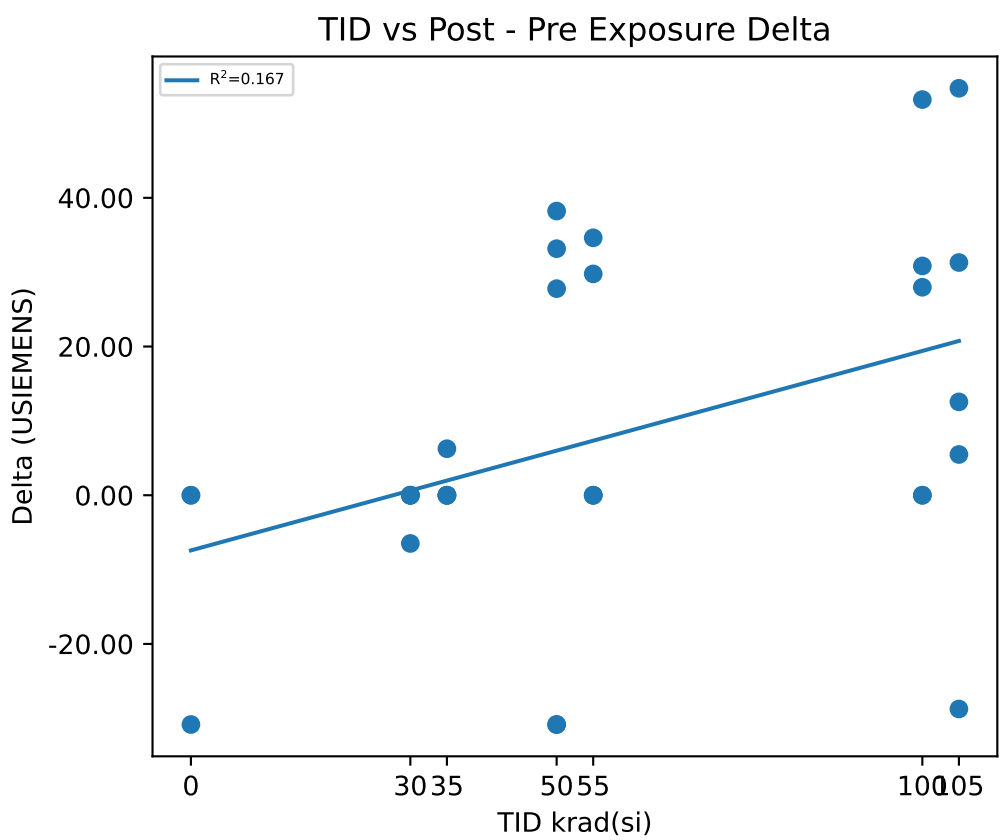
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.1637	-0.0463	0.1174
2	0	CU2	-0.1217	0.0177	0.1394
3	0	CU3	-0.2011	-0.0057	0.1954
11	30	Unbiased-30krad	-0.159	-0.0541	0.1049
12	30	Unbiased-30krad	-0.0485	-0.065	-0.0165
13	30	Unbiased-30krad	-0.1357	0.0348	0.1705
14	30	Unbiased-30krad	-0.0765	0.0177	0.0942
15	30	Unbiased-30krad	-0.1279	0.0536	0.1815
16	35	Biased-30krad	-0.0532	0.038	0.0912
17	35	Biased-30krad	-0.1232	-0.0291	0.0941
18	35	Biased-30krad	-0.1341	0.0161	0.1502
19	35	Biased-30krad	-0.1404	0.0442	0.1846
20	35	Biased-30krad	-0.1263	0.0099	0.1362
30	50	Unbiased-50krad	-0.1388	-0.0104	0.1284
31	50	Unbiased-50krad	-0.0703	0.0177	0.088
32	50	Unbiased-50krad	-0.1466	-0.0666	0.08
33	50	Unbiased-50krad	-0.1637	-0.0245	0.1392
34	50	Unbiased-50krad	-0.131	-0.012	0.119
40	55	Biased-50krad	-0.1186	-0.0167	0.1019
41	55	Biased-50krad	-0.0983	0.0146	0.1129
42	55	Biased-50krad	-0.0578	0.0068	0.0646
43	55	Biased-50krad	-0.0781	-0.0276	0.0505
44	55	Biased-50krad	-0.1372	-0.0369	0.1003
45	100	Unbiased-100krad	-0.0936	0.038	0.1316
46	100	Unbiased-100krad	-0.0734	-0.0307	0.0427
47	100	Unbiased-100krad	-0.2353	-0.09	0.1453
48	100	Unbiased-100krad	-0.1154	0.0317	0.1471
49	100	Unbiased-100krad	-0.0547	0.0161	0.0708
50	105	Biased-100krad	-0.0329	-0.0853	-0.0524
51	105	Biased-100krad	-0.0625	0.0208	0.0833
52	105	Biased-100krad	-0.1279	-0.0338	0.0941
53	105	Biased-100krad	-0.0641	-0.0682	-0.0041
54	105	Biased-100krad	-0.1014	-0.051	0.0504

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2011	-0.16217	-0.1217	0.039722	-0.0463	-0.011433	0.0177	0.032383	0.1174	0.15073	0.1954	0.040216
30	-0.159	-0.10952	-0.0485	0.045512	-0.065	-0.0026	0.0536	0.053655	-0.0165	0.10692	0.1815	0.079062
35	-0.1404	-0.11544	-0.0532	0.035437	-0.0291	0.01582	0.0442	0.028941	0.0912	0.13126	0.1846	0.039414
50	-0.1637	-0.13008	-0.0703	0.035545	-0.0666	-0.01916	0.0177	0.030683	0.08	0.11092	0.1392	0.025749
55	-0.1372	-0.098	-0.0578	0.031516	-0.0369	-0.01196	0.0146	0.022059	0.0505	0.08604	0.1129	0.026922
100	-0.2353	-0.11448	-0.0547	0.071231	-0.09	-0.00698	0.038	0.053635	0.0427	0.1075	0.1471	0.047759
105	-0.1279	-0.07776	-0.0329	0.037097	-0.0853	-0.0435	0.0208	0.04075	-0.0524	0.03426	0.0941	0.0617

Device Test: 39.20 _EA|Transconductance/VSNS4/7/7///90.9/634//0///@EA_GM_25C





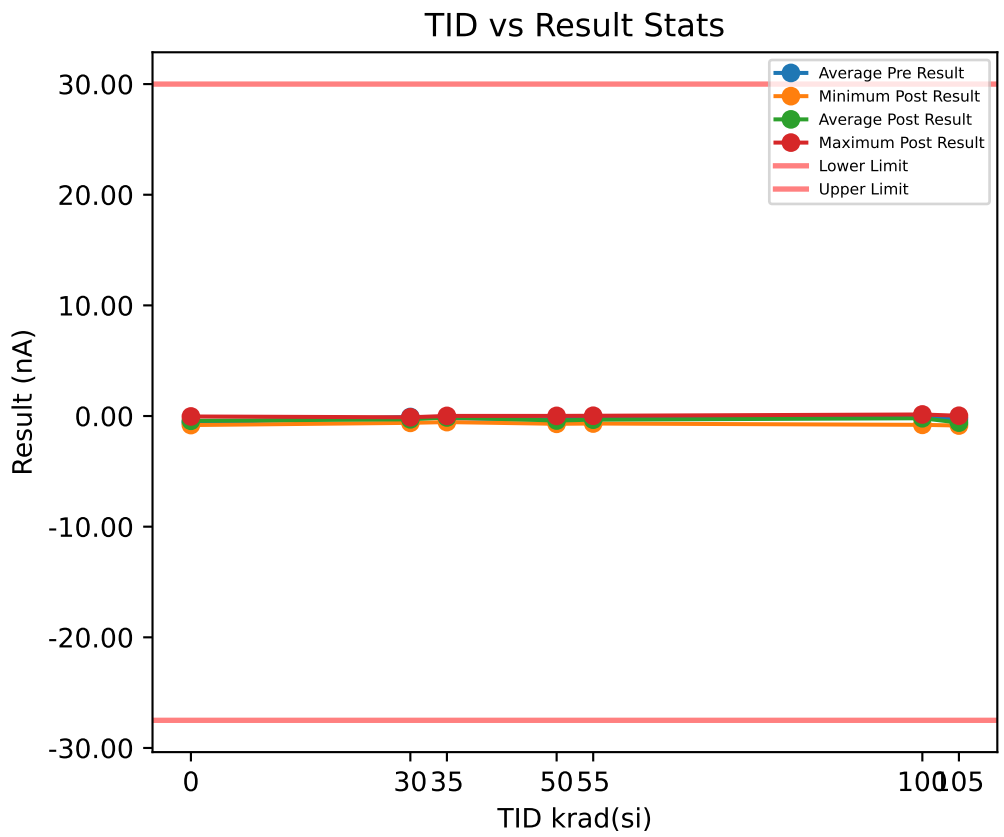
Test Results (Lower Limit = 1328.0, Upper Limit = 2016.0 (USIEMENS))

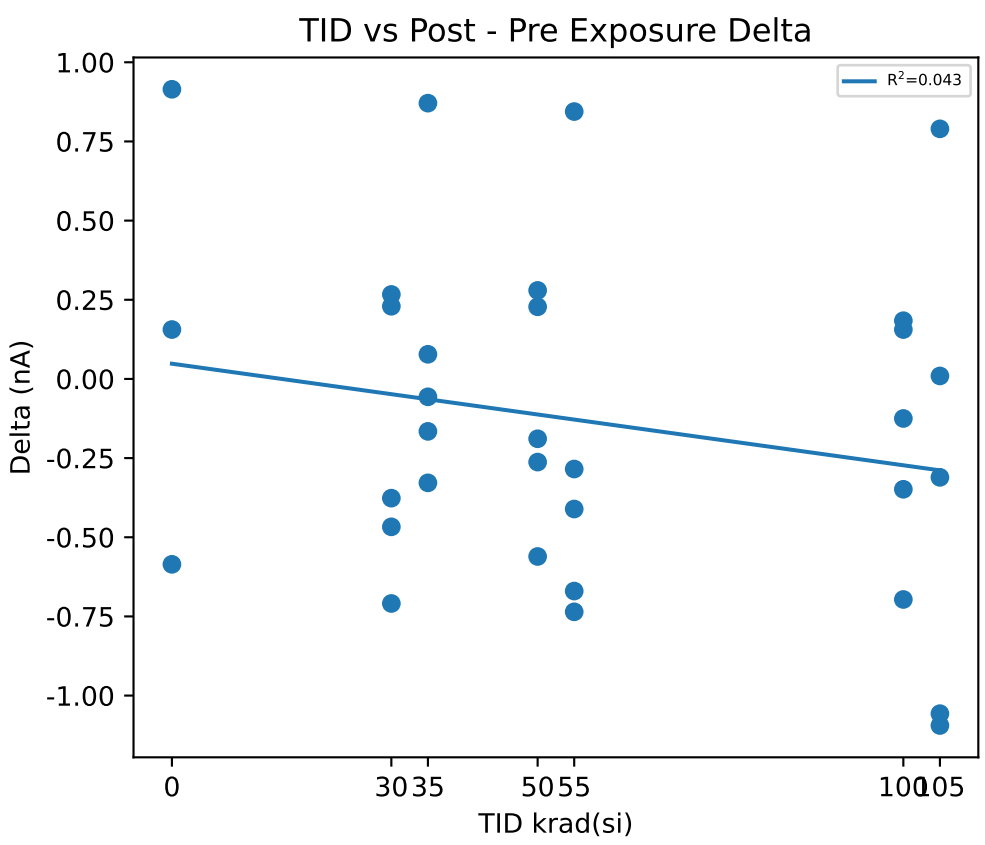
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1745.3	1714.5	-30.836
2	0	CU2	1656	1656	0
3	0	CU3	1714.5	1714.5	0
11	30	Unbiased-30krad	1745.3	1745.3	0
12	30	Unbiased-30krad	1777.3	1770.8	-6.4865
13	30	Unbiased-30krad	1684.7	1684.7	0
14	30	Unbiased-30krad	1601.3	1601.3	0
15	30	Unbiased-30krad	1656	1656	0
16	35	Biased-30krad	1656	1656	0
17	35	Biased-30krad	1656	1656	0
18	35	Biased-30krad	1656	1656	0
19	35	Biased-30krad	1739.1	1745.3	6.2557
20	35	Biased-30krad	1656	1656	0
30	50	Unbiased-50krad	1777.3	1810.5	33.159
31	50	Unbiased-50krad	1745.3	1714.5	-30.836
32	50	Unbiased-50krad	1628.2	1656	27.785
33	50	Unbiased-50krad	1745.3	1714.5	-30.836
34	50	Unbiased-50krad	1739.1	1777.3	38.222
40	55	Biased-50krad	1580.5	1580.5	0
41	55	Biased-50krad	1684.7	1714.5	29.766
42	55	Biased-50krad	1745.3	1745.3	0
43	55	Biased-50krad	1656	1690.6	34.62
44	55	Biased-50krad	1606.6	1606.6	0
45	100	Unbiased-100krad	1580.5	1633.7	53.215
46	100	Unbiased-100krad	1580.5	1580.5	0
47	100	Unbiased-100krad	1684.7	1684.7	0
48	100	Unbiased-100krad	1714.5	1745.3	30.836
49	100	Unbiased-100krad	1633.7	1661.7	27.974
50	105	Biased-100krad	1684.7	1656	-28.75
51	105	Biased-100krad	1575.3	1606.6	31.298
52	105	Biased-100krad	1690.6	1745.3	54.732
53	105	Biased-100krad	1628.2	1633.7	5.4821
54	105	Biased-100krad	1739.1	1751.6	12.557

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1656	1705.3	1745.3	45.385	1656	1695	1714.5	33.784	-30.836	-10.279	0	17.803
30	1601.3	1692.9	1777.3	70.156	1601.3	1691.6	1770.8	68.24	-6.4865	-1.2973	0	2.9009
35	1656	1672.6	1739.1	37.162	1656	1673.9	1745.3	39.959	0	1.2511	6.2557	2.7976
50	1628.2	1727.1	1777.3	57.25	1656	1734.6	1810.5	60.347	-30.836	7.4985	38.222	35.189
55	1580.5	1654.6	1745.3	65.076	1580.5	1667.5	1745.3	70.853	0	12.877	34.62	17.716
100	1580.5	1638.8	1714.5	60.564	1580.5	1661.2	1745.3	61.049	0	22.405	53.215	22.668
105	1575.3	1663.6	1739.1	63.081	1606.6	1678.7	1751.6	66.137	-28.75	15.064	54.732	31.044

Device Test: 39.3 _EA|Leakage/VSNS3/7/7///90.9/634//0///@IVSNS_LKG





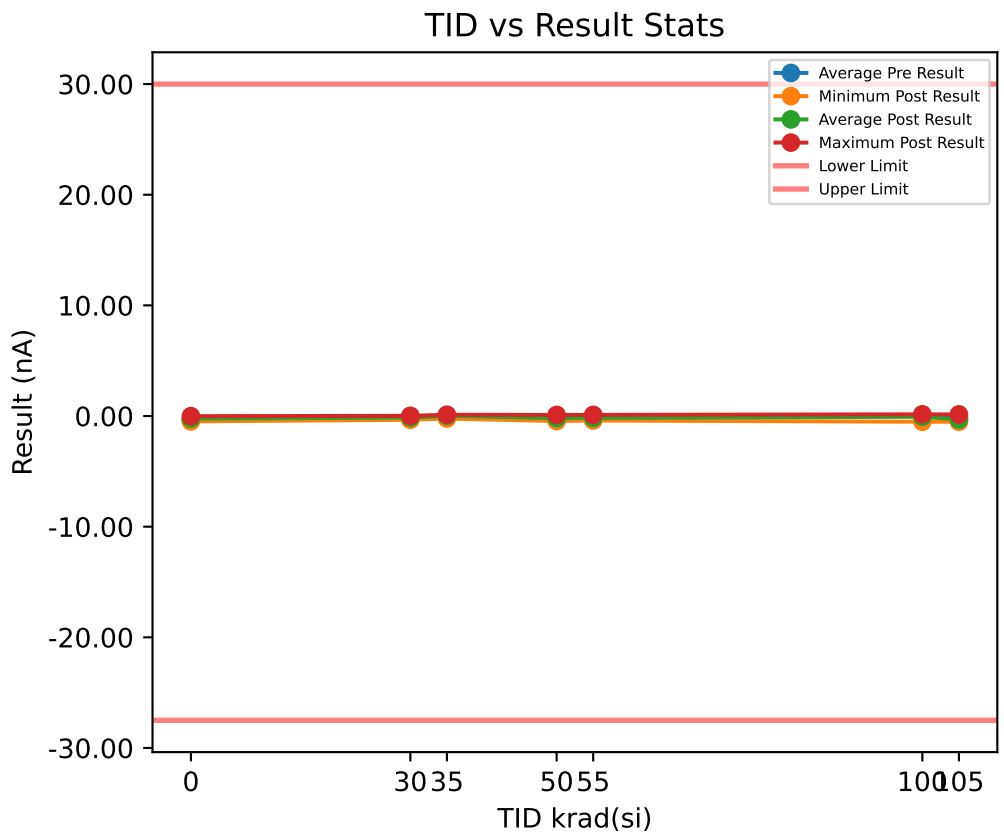
Test Results (Lower Limit = -27.5, Upper Limit = 30.0 (nA))

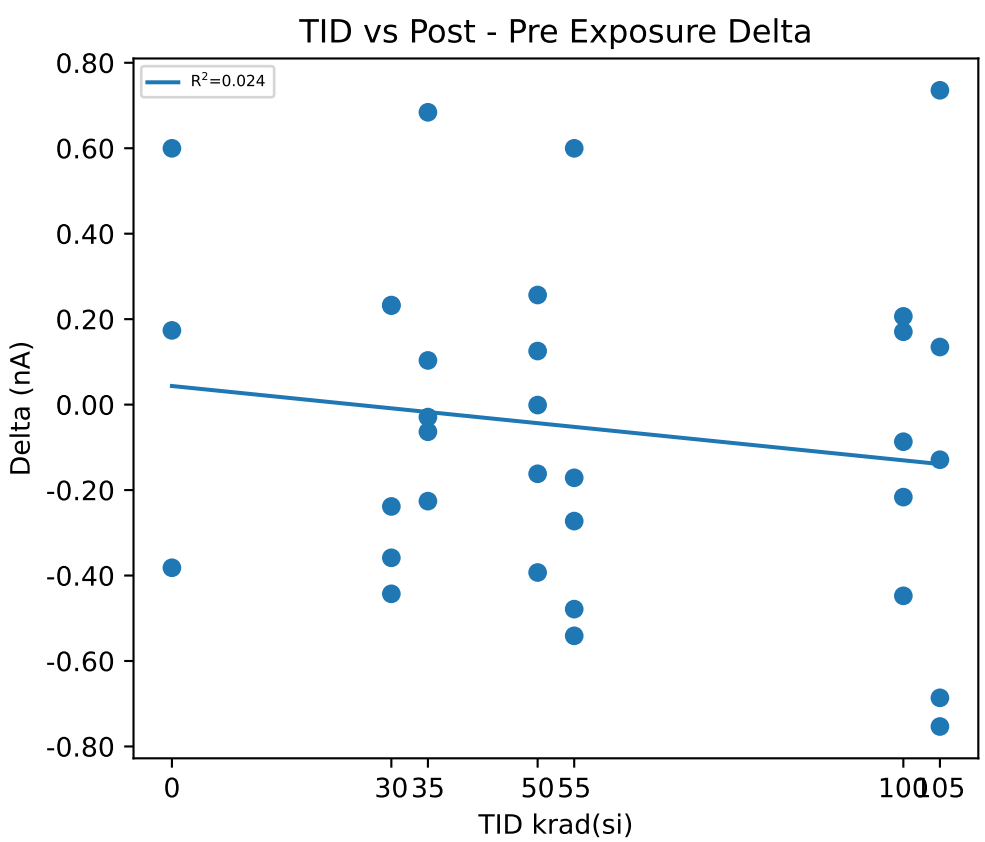
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.231	-0.8165	-0.5855
2	0	CU2	-0.587	-0.431	0.156
3	0	CU3	-0.9539	-0.0392	0.9147
11	30	Unbiased-30krad	-0.8462	-0.6167	0.2295
12	30	Unbiased-30krad	0.4061	-0.303	-0.7091
13	30	Unbiased-30krad	0.2812	-0.1859	-0.4671
14	30	Unbiased-30krad	0.1063	-0.2702	-0.3765
15	30	Unbiased-30krad	-0.3809	-0.1141	0.2668
16	35	Biased-30krad	0.2359	-0.0923	-0.3282
17	35	Biased-30krad	-0.3824	-0.548	-0.1656
18	35	Biased-30krad	-0.8602	0.0107	0.8709
19	35	Biased-30krad	-0.0686	0.0092	0.0778
20	35	Biased-30krad	0.0329	-0.0236	-0.0565
30	50	Unbiased-50krad	0.1266	-0.4341	-0.5607
31	50	Unbiased-50krad	0.2749	0.0123	-0.2626
32	50	Unbiased-50krad	-0.576	-0.3482	0.2278
33	50	Unbiased-50krad	-0.3684	-0.5574	-0.189
34	50	Unbiased-50krad	-0.9836	-0.7041	0.2795
40	55	Biased-50krad	-0.8196	0.0248	0.8444
41	55	Biased-50krad	0.2796	-0.0049	-0.2845
42	55	Biased-50krad	0.136	-0.5995	-0.7355
43	55	Biased-50krad	0.0204	-0.3904	-0.4108
44	55	Biased-50krad	-0.0077	-0.6776	-0.6699
45	100	Unbiased-100krad	-0.142	0.0139	0.1559
46	100	Unbiased-100krad	0.328	-0.3685	-0.6965
47	100	Unbiased-100krad	-0.6713	-0.7962	-0.1249
48	100	Unbiased-100krad	0.3514	0.0029	-0.3485
49	100	Unbiased-100krad	-0.042	0.1419	0.1839
50	105	Biased-100krad	0.4123	-0.6448	-1.0571
51	105	Biased-100krad	-0.765	0.0248	0.7898
52	105	Biased-100krad	-0.868	-0.8586	0.0094
53	105	Biased-100krad	0.2921	-0.8024	-1.0945
54	105	Biased-100krad	-0.3902	-0.701	-0.3108

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.9539	-0.59063	-0.231	0.36146	-0.8165	-0.4289	-0.0392	0.38865	-0.5855	0.16173	0.9147	0.75012
30	-0.8462	-0.0867	0.4061	0.51934	-0.6167	-0.29798	-0.1141	0.19284	-0.7091	-0.21128	0.2668	0.43687
35	-0.8602	-0.20848	0.2359	0.42729	-0.548	-0.1288	0.0107	0.23803	-0.3282	0.07968	0.8709	0.46667
50	-0.9836	-0.3053	0.2749	0.51491	-0.7041	-0.4063	0.0123	0.26967	-0.5607	-0.101	0.2795	0.35287
55	-0.8196	-0.07826	0.2796	0.42961	-0.6776	-0.32952	0.0248	0.32737	-0.7355	-0.25126	0.8444	0.63968
100	-0.6713	-0.03518	0.3514	0.41757	-0.7962	-0.2012	0.1419	0.38329	-0.6965	-0.16602	0.1839	0.36826
105	-0.868	-0.26376	0.4123	0.59126	-0.8586	-0.5964	0.0248	0.3572	-1.0945	-0.33264	0.7898	0.78782

Device Test: 39.4 _EA|Leakage/VSNS4/7/7///90.9/634//0///@IVSNS_LKG





Test Results (Lower Limit = -27.5, Upper Limit = 30.0 (nA))

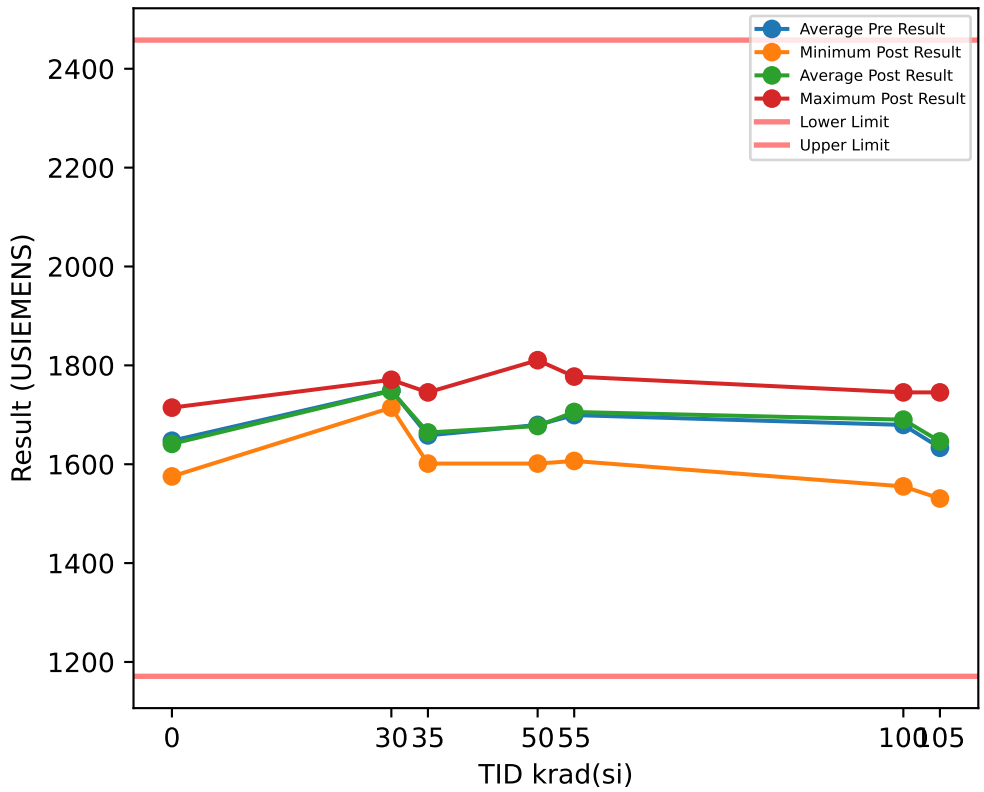
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.1015	-0.4833	-0.3818
2	0	CU2	-0.384	-0.2103	0.1737
3	0	CU3	-0.6119	-0.0121	0.5998
11	30	Unbiased-30krad	-0.5698	-0.3382	0.2316
12	30	Unbiased-30krad	0.3184	-0.1244	-0.4428
13	30	Unbiased-30krad	0.2731	-0.0854	-0.3585
14	30	Unbiased-30krad	0.0967	-0.1416	-0.2383
15	30	Unbiased-30krad	-0.217	0.016	0.233
16	35	Biased-30krad	0.2544	0.0285	-0.2259
17	35	Biased-30krad	-0.2014	-0.2306	-0.0292
18	35	Biased-30krad	-0.5885	0.0956	0.6841
19	35	Biased-30krad	0.0109	0.1143	0.1034
20	35	Biased-30krad	0.1326	0.0691	-0.0635
30	50	Unbiased-50krad	0.1467	-0.2462	-0.3929
31	50	Unbiased-50krad	0.259	0.0971	-0.1619
32	50	Unbiased-50krad	-0.4043	-0.1478	0.2565
33	50	Unbiased-50krad	-0.2077	-0.2087	-0.001
34	50	Unbiased-50krad	-0.5807	-0.4553	0.1254
40	55	Biased-50krad	-0.512	0.0878	0.5998
41	55	Biased-50krad	0.2731	0.1018	-0.1713
42	55	Biased-50krad	0.1467	-0.3944	-0.5411
43	55	Biased-50krad	0.028	-0.2446	-0.2726
44	55	Biased-50krad	0.0733	-0.4053	-0.4786
45	100	Unbiased-100krad	-0.0219	0.1486	0.1705
46	100	Unbiased-100krad	0.2341	-0.2134	-0.4475
47	100	Unbiased-100krad	-0.4293	-0.5161	-0.0868
48	100	Unbiased-100krad	0.309	0.0925	-0.2165
49	100	Unbiased-100krad	-0.0516	0.1549	0.2065
50	105	Biased-100krad	0.3371	-0.3491	-0.6862
51	105	Biased-100krad	-0.5901	0.1455	0.7356
52	105	Biased-100krad	-0.5729	-0.4381	0.1348
53	105	Biased-100krad	0.2356	-0.5177	-0.7533
54	105	Biased-100krad	-0.2763	-0.4053	-0.129

Test Statistics (nA)

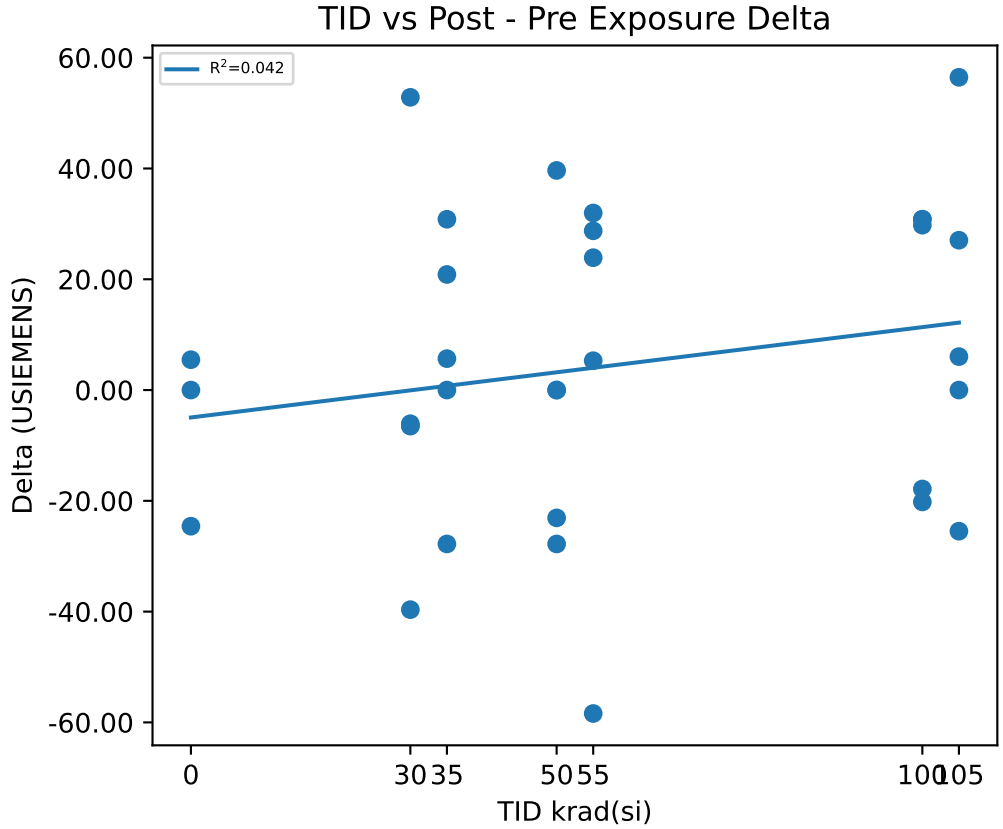
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.6119	-0.3658	-0.1015	0.25569	-0.4833	-0.23523	-0.0121	0.23659	-0.3818	0.13057	0.5998	0.49222
30	-0.5698	-0.01972	0.3184	0.37254	-0.3382	-0.13472	0.016	0.12914	-0.4428	-0.115	0.233	0.32526
35	-0.5885	-0.0784	0.2544	0.33113	-0.2306	0.01538	0.1143	0.14123	-0.2259	0.09378	0.6841	0.35022
50	-0.5807	-0.1574	0.259	0.35656	-0.4553	-0.19218	0.0971	0.19879	-0.3929	-0.03478	0.2565	0.25301
55	-0.512	0.00182	0.2731	0.30182	-0.4053	-0.17094	0.1018	0.25081	-0.5411	-0.17276	0.5998	0.45717
100	-0.4293	0.00806	0.309	0.29043	-0.5161	-0.0667	0.1549	0.29338	-0.4475	-0.07476	0.2065	0.27314
105	-0.5901	-0.17332	0.3371	0.43924	-0.5177	-0.31294	0.1455	0.26344	-0.7533	-0.13962	0.7356	0.61579

Device Test: 39.5 _EA|Transconductance/VSNS1/7/7///90.9/634//0///@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

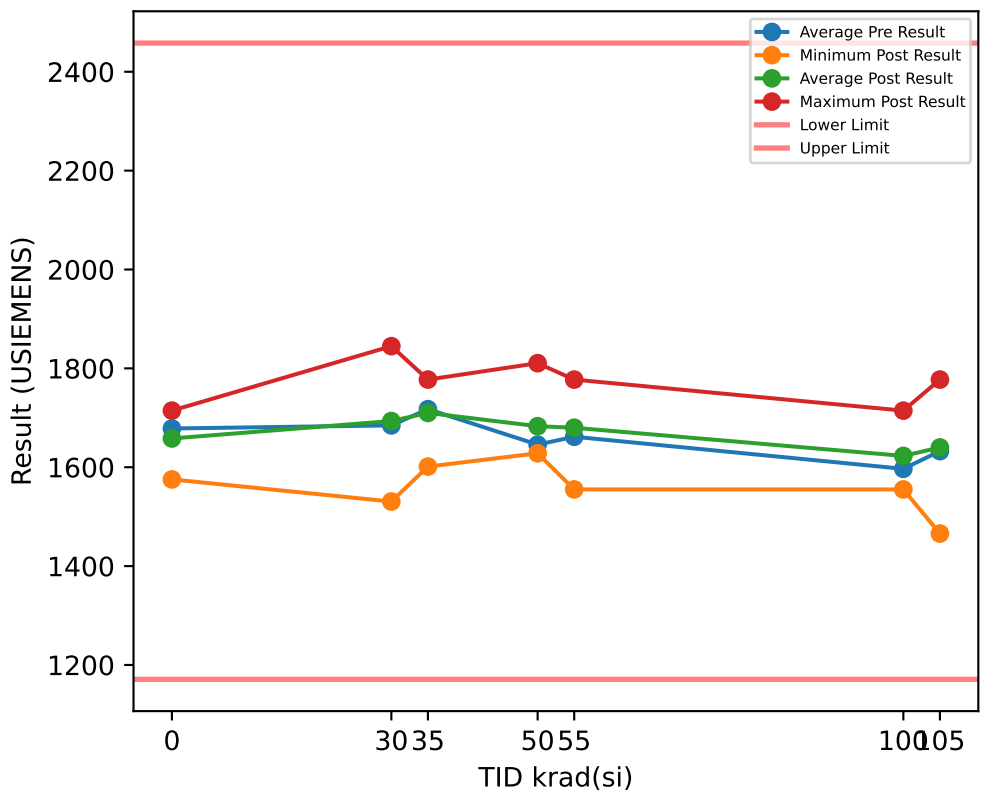
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1739.1	1714.5	-24.581
2	0	CU2	1628.2	1633.7	5.4821
3	0	CU3	1575.3	1575.3	0
11	30	Unbiased-30krad	1661.7	1714.5	52.844
12	30	Unbiased-30krad	1777.3	1770.8	-6.4865
13	30	Unbiased-30krad	1810.5	1770.8	-39.645
14	30	Unbiased-30krad	1720.6	1714.5	-6.0798
15	30	Unbiased-30krad	1777.3	1770.8	-6.4865
16	35	Biased-30krad	1580.5	1601.3	20.864
17	35	Biased-30krad	1714.5	1745.3	30.836
18	35	Biased-30krad	1656	1661.7	5.6712
19	35	Biased-30krad	1684.7	1684.7	0
20	35	Biased-30krad	1656	1628.2	-27.785
30	50	Unbiased-50krad	1656	1628.2	-27.785
31	50	Unbiased-50krad	1684.7	1684.7	0
32	50	Unbiased-50krad	1684.7	1661.7	-23.079
33	50	Unbiased-50krad	1601.3	1601.3	0
34	50	Unbiased-50krad	1770.8	1810.5	39.645
40	55	Biased-50krad	1745.3	1777.3	31.966
41	55	Biased-50krad	1601.3	1606.6	5.3024
42	55	Biased-50krad	1803.7	1745.3	-58.394
43	55	Biased-50krad	1690.6	1714.5	23.895
44	55	Biased-50krad	1656	1684.7	28.75
45	100	Unbiased-100krad	1714.5	1745.3	30.836
46	100	Unbiased-100krad	1575.3	1555.1	-20.197
47	100	Unbiased-100krad	1684.7	1714.5	29.766
48	100	Unbiased-100krad	1714.5	1745.3	30.836
49	100	Unbiased-100krad	1708.5	1690.6	-17.858
50	105	Biased-100krad	1708.5	1714.5	6.037
51	105	Biased-100krad	1550.2	1606.6	56.463
52	105	Biased-100krad	1606.6	1633.7	27.048
53	105	Biased-100krad	1530.6	1530.6	0
54	105	Biased-100krad	1770.8	1745.3	-25.479

Test Statistics (USIEMENS)

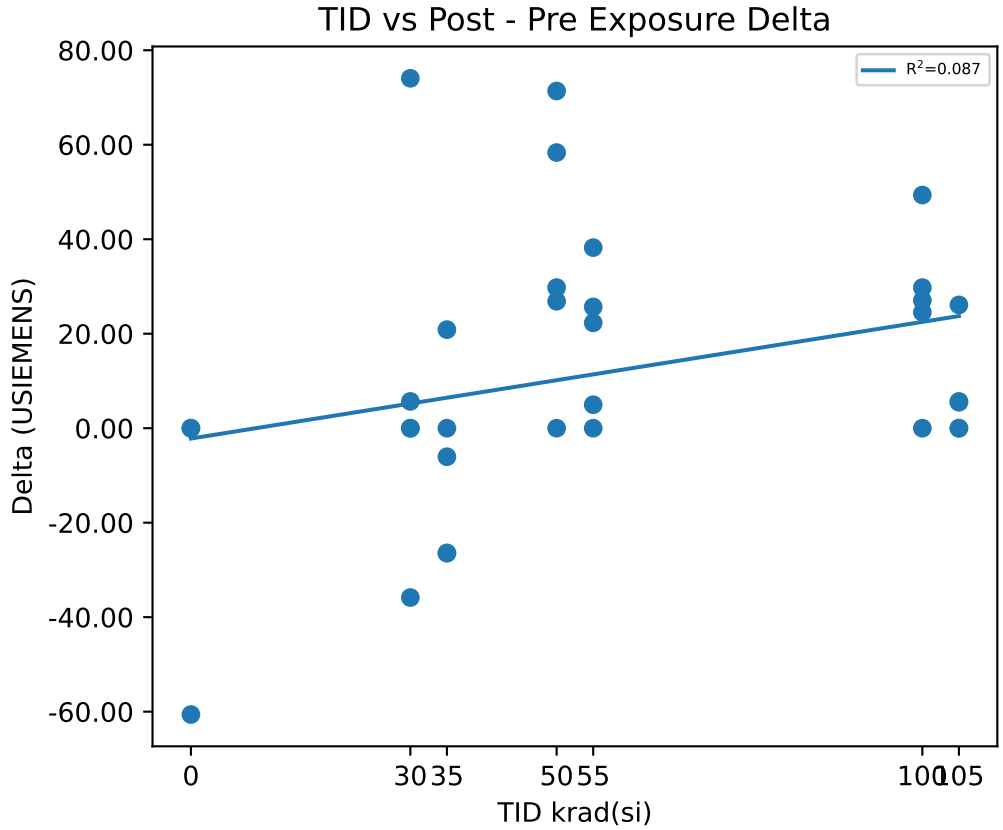
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1647.5	1739.1	83.568	1575.3	1641.2	1714.5	69.884	-24.581	-6.3662	5.4821	16.011
30	1661.7	1749.5	1810.5	58.769	1714.5	1748.3	1770.8	30.845	-39.645	-1.1707	52.844	33.461
35	1580.5	1658.3	1714.5	49.814	1601.3	1664.3	1745.3	55.362	-27.785	5.9174	30.836	22.446
50	1601.3	1679.5	1770.8	61.353	1601.3	1677.3	1810.5	80.954	-27.785	-2.2437	39.645	26.698
55	1601.3	1699.4	1803.7	78.382	1606.6	1705.7	1777.3	65.248	-58.394	6.3039	31.966	37.612
100	1575.3	1679.5	1714.5	59.511	1555.1	1690.2	1745.3	78.918	-20.197	10.677	30.836	27.132
105	1530.6	1633.3	1770.8	103.35	1530.6	1646.2	1745.3	85.989	-25.479	12.814	56.463	30.759

Device Test: 39.6 _EA|Transconductance/VSNS2/7/7///90.9/634//0///@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



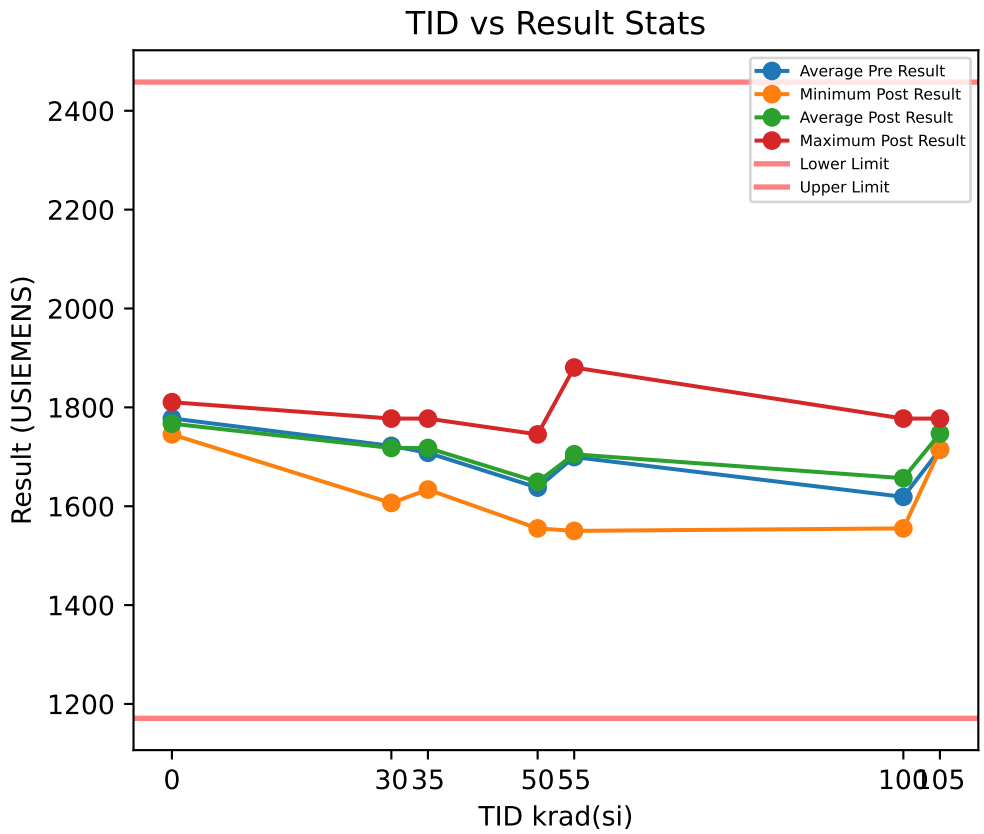
Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

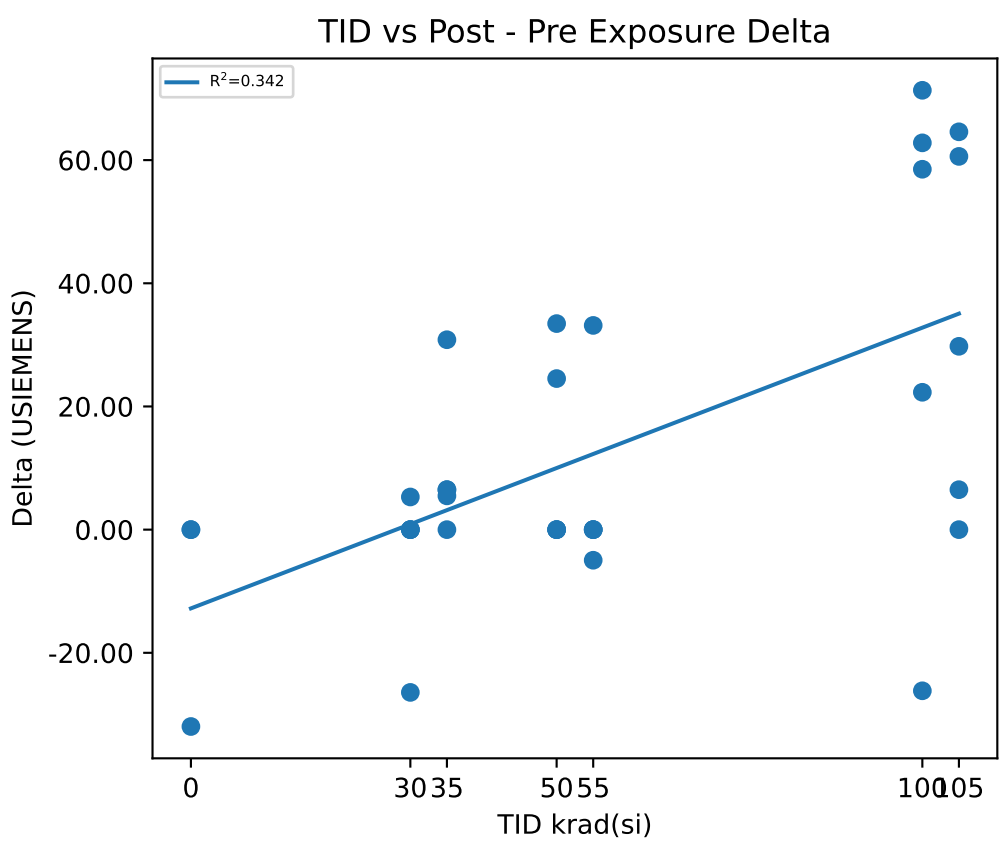
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1714.5	1714.5	0
2	0	CU2	1575.3	1575.3	0
3	0	CU3	1745.3	1684.7	-60.602
11	30	Unbiased-30krad	1720.6	1684.7	-35.845
12	30	Unbiased-30krad	1745.3	1745.3	0
13	30	Unbiased-30krad	1770.8	1844.9	74.065
14	30	Unbiased-30krad	1530.6	1530.6	0
15	30	Unbiased-30krad	1656	1661.7	5.6712
16	35	Biased-30krad	1684.7	1684.7	0
17	35	Biased-30krad	1803.7	1777.3	-26.428
18	35	Biased-30krad	1714.5	1708.5	-6.037
19	35	Biased-30krad	1803.7	1777.3	-26.428
20	35	Biased-30krad	1580.5	1601.3	20.864
30	50	Unbiased-50krad	1575.3	1633.7	58.346
31	50	Unbiased-50krad	1601.3	1628.2	26.868
32	50	Unbiased-50krad	1628.2	1628.2	0
33	50	Unbiased-50krad	1684.7	1714.5	29.766
34	50	Unbiased-50krad	1739.1	1810.5	71.38
40	55	Biased-50krad	1633.7	1633.7	0
41	55	Biased-50krad	1739.1	1777.3	38.222
42	55	Biased-50krad	1751.6	1777.3	25.665
43	55	Biased-50krad	1633.7	1656	22.303
44	55	Biased-50krad	1550.2	1555.1	4.9685
45	100	Unbiased-100krad	1555.1	1555.1	0
46	100	Unbiased-100krad	1606.6	1633.7	27.048
47	100	Unbiased-100krad	1606.6	1656	49.351
48	100	Unbiased-100krad	1684.7	1714.5	29.766
49	100	Unbiased-100krad	1530.6	1555.1	24.529
50	105	Biased-100krad	1628.2	1633.7	5.4821
51	105	Biased-100krad	1439.8	1465.9	26.099
52	105	Biased-100krad	1661.7	1661.7	0
53	105	Biased-100krad	1656	1661.7	5.6712
54	105	Biased-100krad	1777.3	1777.3	0

Test Statistics (USIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1678.4	1745.3	90.57	1575.3	1658.2	1714.5	73.281	-60.602	-20.201	0	34.989
30	1530.6	1684.7	1770.8	96.11	1530.6	1693.4	1844.9	115.36	-35.845	8.7781	74.065	40.054
35	1580.5	1717.4	1803.7	93.183	1601.3	1709.8	1777.3	73.329	-26.428	-7.6059	20.864	19.871
50	1575.3	1645.7	1739.1	66.086	1628.2	1683	1810.5	80.12	0	37.272	71.38	28.113
55	1550.2	1661.7	1751.6	83.793	1555.1	1679.9	1777.3	96.499	0	18.232	38.222	15.65
100	1530.6	1596.8	1684.7	59.251	1555.1	1622.9	1714.5	68.528	0	26.139	49.351	17.597
105	1439.8	1632.6	1777.3	122	1465.9	1640	1777.3	111.97	0	7.4504	26.099	10.791

Device Test: 39.7 _EA|Transconductance/VSNS3/7/7///90.9/634//0///@EA_GM





Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

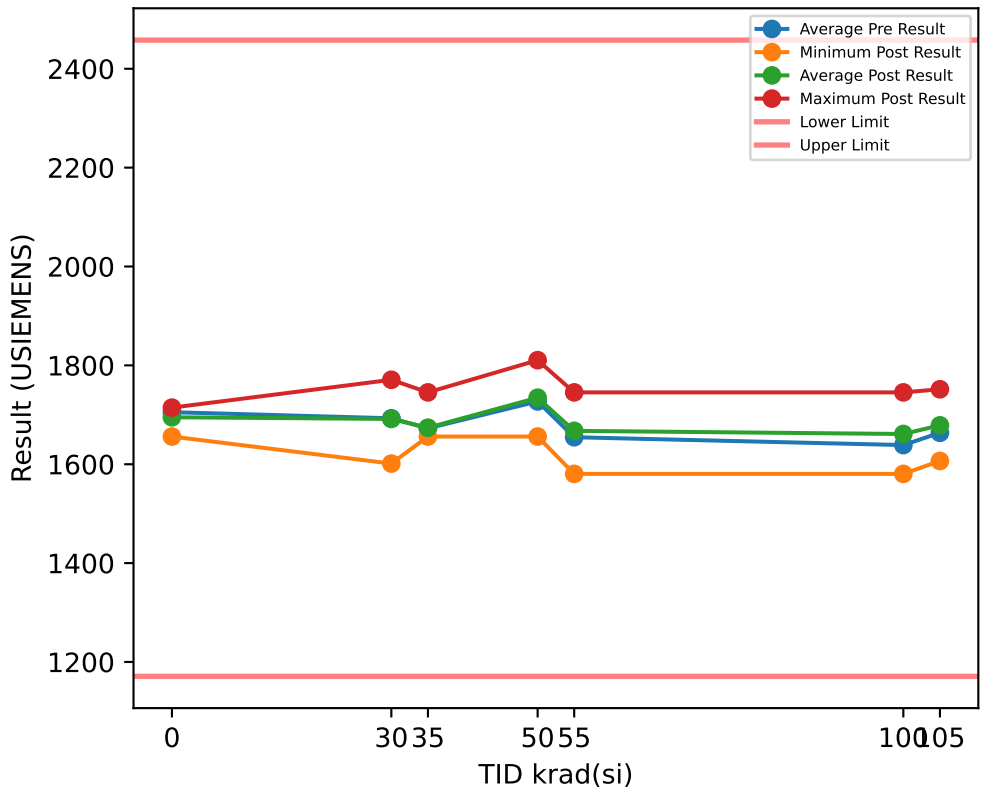
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1810.5	1810.5	0
2	0	CU2	1745.3	1745.3	0
3	0	CU3	1777.3	1745.3	-31.966
11	30	Unbiased-30krad	1745.3	1745.3	0
12	30	Unbiased-30krad	1714.5	1714.5	0
13	30	Unbiased-30krad	1745.3	1745.3	0
14	30	Unbiased-30krad	1601.3	1606.6	5.3024
15	30	Unbiased-30krad	1803.7	1777.3	-26.428
16	35	Biased-30krad	1656	1656	0
17	35	Biased-30krad	1714.5	1745.3	30.836
18	35	Biased-30krad	1770.8	1777.3	6.4865
19	35	Biased-30krad	1770.8	1777.3	6.4865
20	35	Biased-30krad	1628.2	1633.7	5.4821
30	50	Unbiased-50krad	1530.6	1555.1	24.529
31	50	Unbiased-50krad	1628.2	1661.7	33.456
32	50	Unbiased-50krad	1628.2	1628.2	0
33	50	Unbiased-50krad	1656	1656	0
34	50	Unbiased-50krad	1745.3	1745.3	0
40	55	Biased-50krad	1777.3	1810.5	33.159
41	55	Biased-50krad	1628.2	1628.2	0
42	55	Biased-50krad	1880.6	1880.6	0
43	55	Biased-50krad	1555.1	1550.2	-4.9685
44	55	Biased-50krad	1656	1656	0
45	100	Unbiased-100krad	1606.6	1580.5	-26.167
46	100	Unbiased-100krad	1483.8	1555.1	71.337
47	100	Unbiased-100krad	1633.7	1656	22.303
48	100	Unbiased-100krad	1714.5	1777.3	62.802
49	100	Unbiased-100krad	1656	1714.5	58.515
50	105	Biased-100krad	1777.3	1777.3	0
51	105	Biased-100krad	1684.7	1714.5	29.766
52	105	Biased-100krad	1684.7	1745.3	60.602
53	105	Biased-100krad	1656	1720.6	64.595
54	105	Biased-100krad	1770.8	1777.3	6.4865

Test Statistics (USIEMENS)

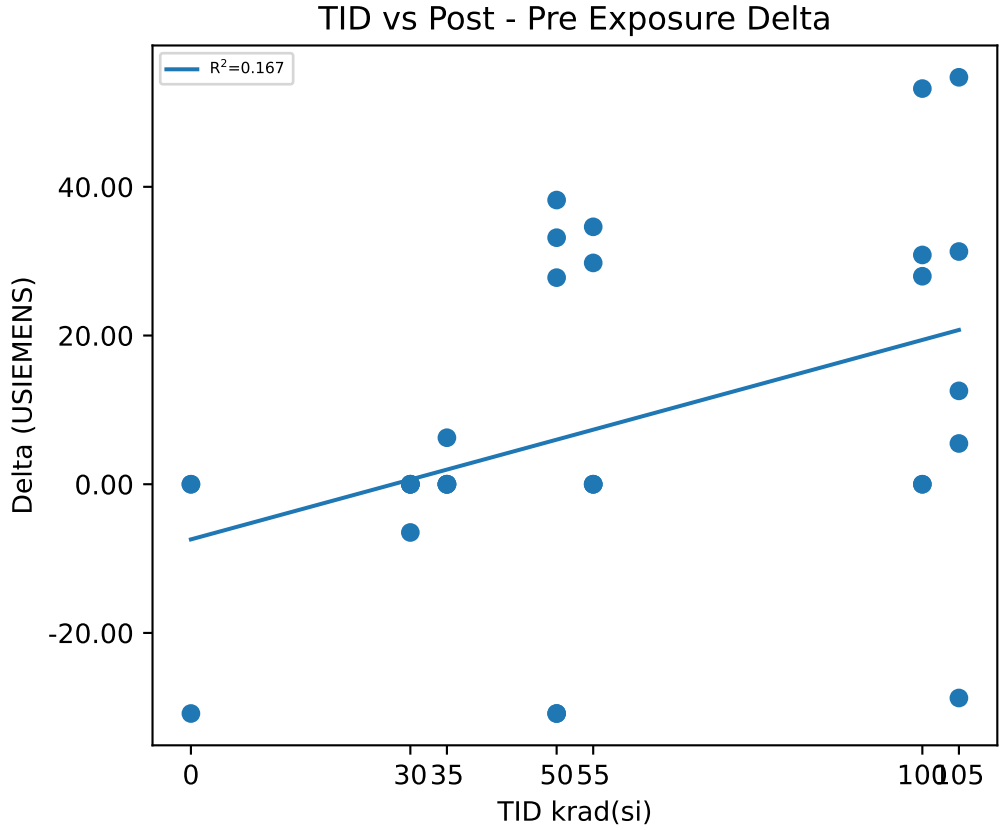
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1745.3	1777.7	1810.5	32.564	1745.3	1767	1810.5	37.6	-31.966	-10.655	0	18.456
30	1601.3	1722.1	1803.7	74.81	1606.6	1717.8	1777.3	66.004	-26.428	-4.2252	5.3024	12.623
35	1628.2	1708.1	1770.8	65.207	1633.7	1717.9	1777.3	68.44	0	9.8583	30.836	12.033
50	1530.6	1637.7	1745.3	76.761	1555.1	1649.3	1745.3	68.432	0	11.597	33.456	16.191
55	1555.1	1699.5	1880.6	129.11	1550.2	1705.1	1880.6	136.24	-4.9685	5.638	33.159	15.534
100	1483.8	1618.9	1714.5	85.345	1555.1	1656.7	1777.3	92.212	-26.167	37.758	71.337	40.345
105	1656	1714.7	1777.3	55.478	1714.5	1747	1777.3	29.973	0	32.29	64.595	29.833

Device Test: 39.8 _EA|Transconductance/VSNS4/7/7///90.9/634//0///@EA_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1171.0, Upper Limit = 2458.0 (USIEMENS))

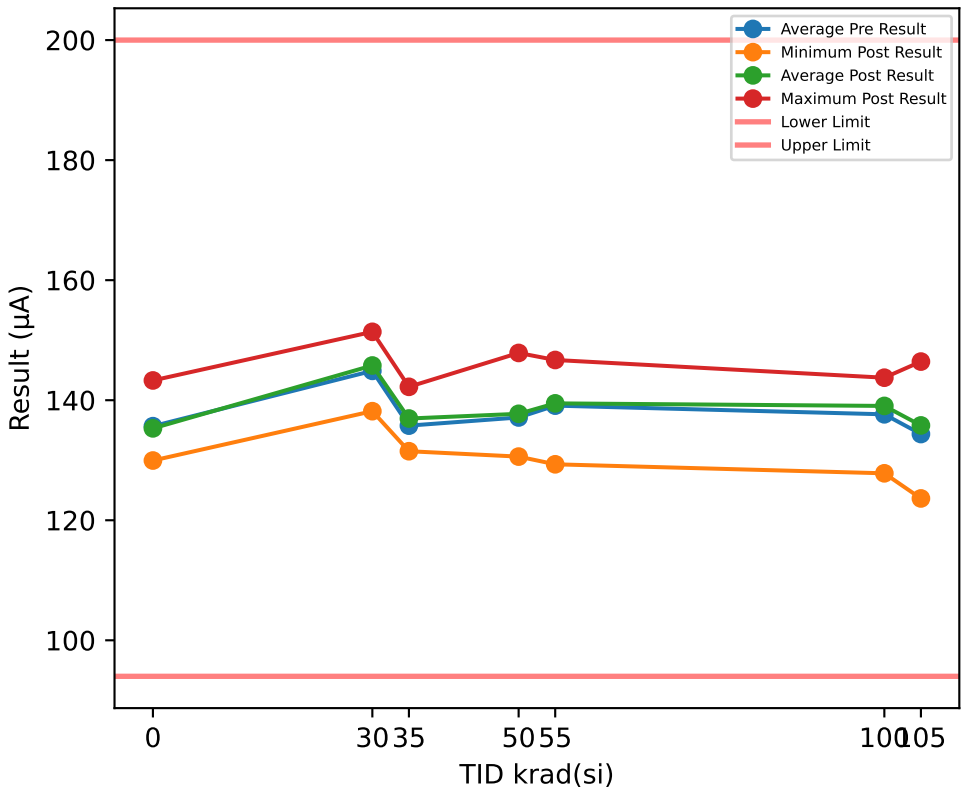
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1745.3	1714.5	-30.836
2	0	CU2	1656	1656	0
3	0	CU3	1714.5	1714.5	0
11	30	Unbiased-30krad	1745.3	1745.3	0
12	30	Unbiased-30krad	1777.3	1770.8	-6.4865
13	30	Unbiased-30krad	1684.7	1684.7	0
14	30	Unbiased-30krad	1601.3	1601.3	0
15	30	Unbiased-30krad	1656	1656	0
16	35	Biased-30krad	1656	1656	0
17	35	Biased-30krad	1656	1656	0
18	35	Biased-30krad	1656	1656	0
19	35	Biased-30krad	1739.1	1745.3	6.2557
20	35	Biased-30krad	1656	1656	0
30	50	Unbiased-50krad	1777.3	1810.5	33.159
31	50	Unbiased-50krad	1745.3	1714.5	-30.836
32	50	Unbiased-50krad	1628.2	1656	27.785
33	50	Unbiased-50krad	1745.3	1714.5	-30.836
34	50	Unbiased-50krad	1739.1	1777.3	38.222
40	55	Biased-50krad	1580.5	1580.5	0
41	55	Biased-50krad	1684.7	1714.5	29.766
42	55	Biased-50krad	1745.3	1745.3	0
43	55	Biased-50krad	1656	1690.6	34.62
44	55	Biased-50krad	1606.6	1606.6	0
45	100	Unbiased-100krad	1580.5	1633.7	53.215
46	100	Unbiased-100krad	1580.5	1580.5	0
47	100	Unbiased-100krad	1684.7	1684.7	0
48	100	Unbiased-100krad	1714.5	1745.3	30.836
49	100	Unbiased-100krad	1633.7	1661.7	27.974
50	105	Biased-100krad	1684.7	1656	-28.75
51	105	Biased-100krad	1575.3	1606.6	31.298
52	105	Biased-100krad	1690.6	1745.3	54.732
53	105	Biased-100krad	1628.2	1633.7	5.4821
54	105	Biased-100krad	1739.1	1751.6	12.557

Test Statistics (USIEMENS)

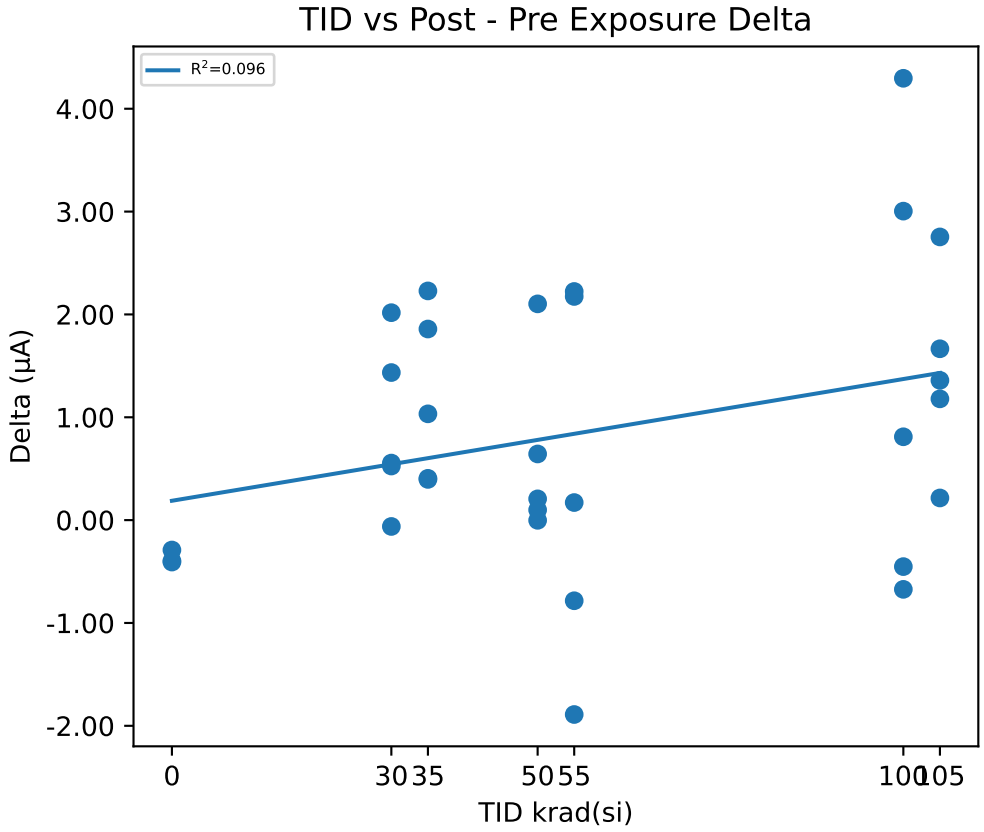
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1656	1705.3	1745.3	45.385	1656	1695	1714.5	33.784	-30.836	-10.279	0	17.803
30	1601.3	1692.9	1777.3	70.156	1601.3	1691.6	1770.8	68.24	-6.4865	-1.2973	0	2.9009
35	1656	1672.6	1739.1	37.162	1656	1673.9	1745.3	39.959	0	1.2511	6.2557	2.7976
50	1628.2	1727.1	1777.3	57.25	1656	1734.6	1810.5	60.347	-30.836	7.4985	38.222	35.189
55	1580.5	1654.6	1745.3	65.076	1580.5	1667.5	1745.3	70.853	0	12.877	34.62	17.716
100	1580.5	1638.8	1714.5	60.564	1580.5	1661.2	1745.3	61.049	0	22.405	53.215	22.668
105	1575.3	1663.6	1739.1	63.081	1606.6	1678.7	1751.6	66.137	-28.75	15.064	54.732	31.044

Device Test: 39.9 _EA|SourceCurrent/COMP1/7/7///90.9/634//0///@EA_SOURCE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



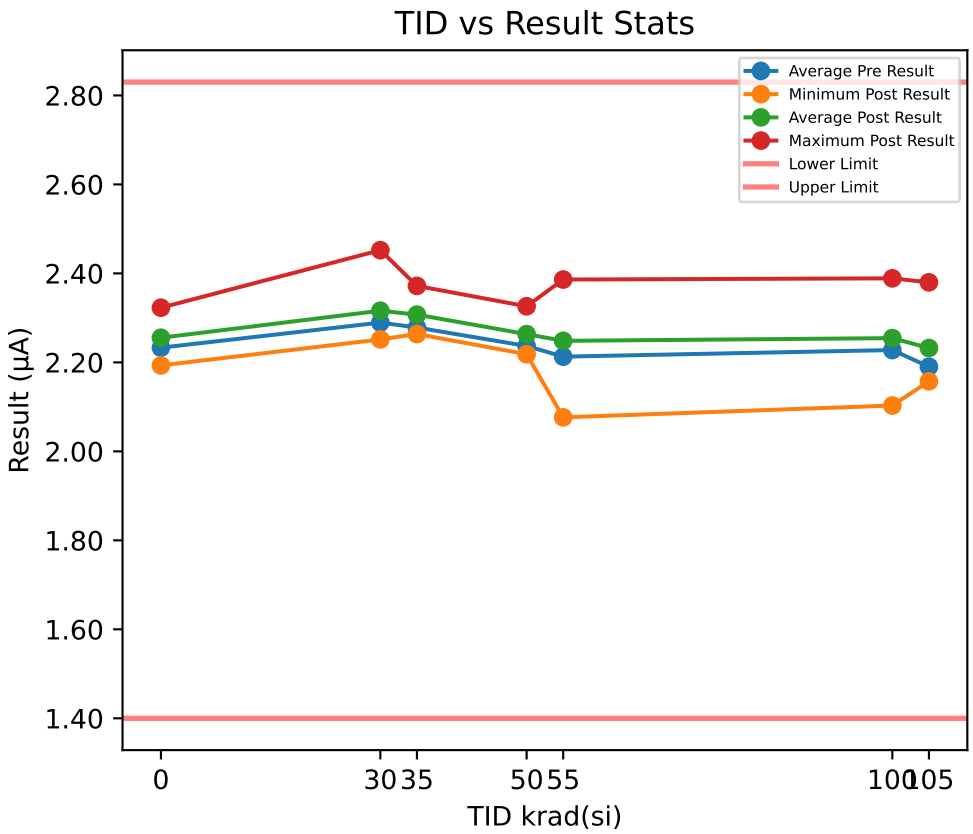
Test Results (Lower Limit = 94.0, Upper Limit = 200.0 (µA))

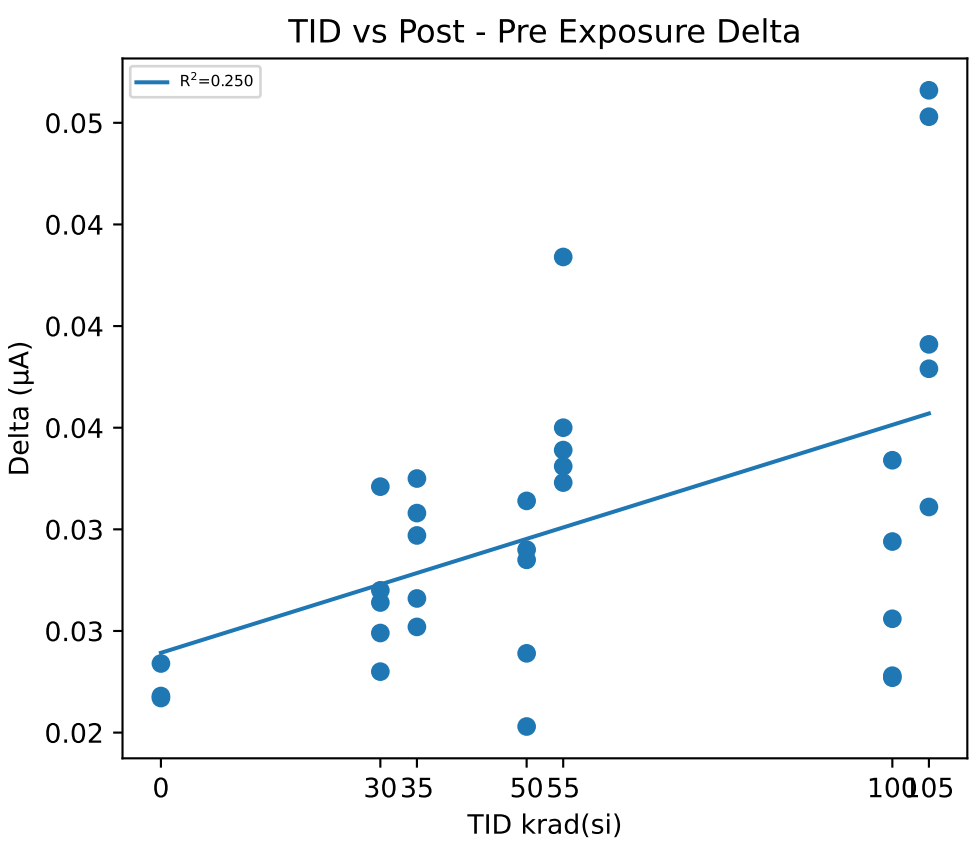
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	143.7	143.29	-0.4078
2	0	CU2	133.08	132.69	-0.396
3	0	CU3	130.24	129.95	-0.2906
11	30	Unbiased-30krad	136.15	138.17	2.0171
12	30	Unbiased-30krad	148.68	149.21	0.526
13	30	Unbiased-30krad	149.96	151.39	1.4349
14	30	Unbiased-30krad	141.09	141.03	-0.0616
15	30	Unbiased-30krad	148.57	149.13	0.5547
16	35	Biased-30krad	129.64	131.5	1.8582
17	35	Biased-30krad	140	142.23	2.2286
18	35	Biased-30krad	135.37	136.4	1.0334
19	35	Biased-30krad	139.15	139.55	0.3959
20	35	Biased-30krad	134.66	135.07	0.4064
30	50	Unbiased-50krad	133.76	133.86	0.0994
31	50	Unbiased-50krad	138.44	139.08	0.6433
32	50	Unbiased-50krad	137.05	137.25	0.2067
33	50	Unbiased-50krad	130.61	130.61	-0.0019
34	50	Unbiased-50krad	145.77	147.88	2.1027
40	55	Biased-50krad	147.49	146.7	-0.784
41	55	Biased-50krad	129.15	129.32	0.1709
42	55	Biased-50krad	147.56	145.67	-1.8901
43	55	Biased-50krad	136.55	138.77	2.2232
44	55	Biased-50krad	134.73	136.91	2.1747
45	100	Unbiased-100krad	139.45	143.75	4.2961
46	100	Unbiased-100krad	128.27	127.82	-0.452
47	100	Unbiased-100krad	138.56	141.56	3.0044
48	100	Unbiased-100krad	141.02	141.83	0.8104
49	100	Unbiased-100krad	140.95	140.27	-0.6732
50	105	Biased-100krad	142.02	143.38	1.3592
51	105	Biased-100krad	129.4	132.16	2.7536
52	105	Biased-100krad	131.73	133.4	1.6661
53	105	Biased-100krad	123.42	123.63	0.2155
54	105	Biased-100krad	145.26	146.44	1.1791

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	130.24	135.68	143.7	7.0936	129.95	135.31	143.29	7.0467	-0.4078	-0.3648	-0.2906	0.064529
30	136.15	144.89	149.96	6.0084	138.17	145.78	151.39	5.8086	-0.0616	0.89422	2.0171	0.82426
35	129.64	135.77	140	4.1318	131.5	136.95	142.23	4.1283	0.3959	1.1845	2.2286	0.83579
50	130.61	137.12	145.77	5.7077	130.61	137.73	147.88	6.5329	-0.0019	0.61004	2.1027	0.86992
55	129.15	139.1	147.56	8.1628	129.32	139.48	146.7	7.0857	-1.8901	0.37894	2.2232	1.8145
100	128.27	137.65	141.02	5.3442	127.82	139.05	143.75	6.3979	-0.6732	1.3971	4.2961	2.1816
105	123.42	134.37	145.26	9.0637	123.63	135.8	146.44	9.1872	0.2155	1.4347	2.7536	0.91522

Device Test: 40.1 _SoftStart|ChargeCurrent/SS1/3/3///90.9/634//0///@I_SS





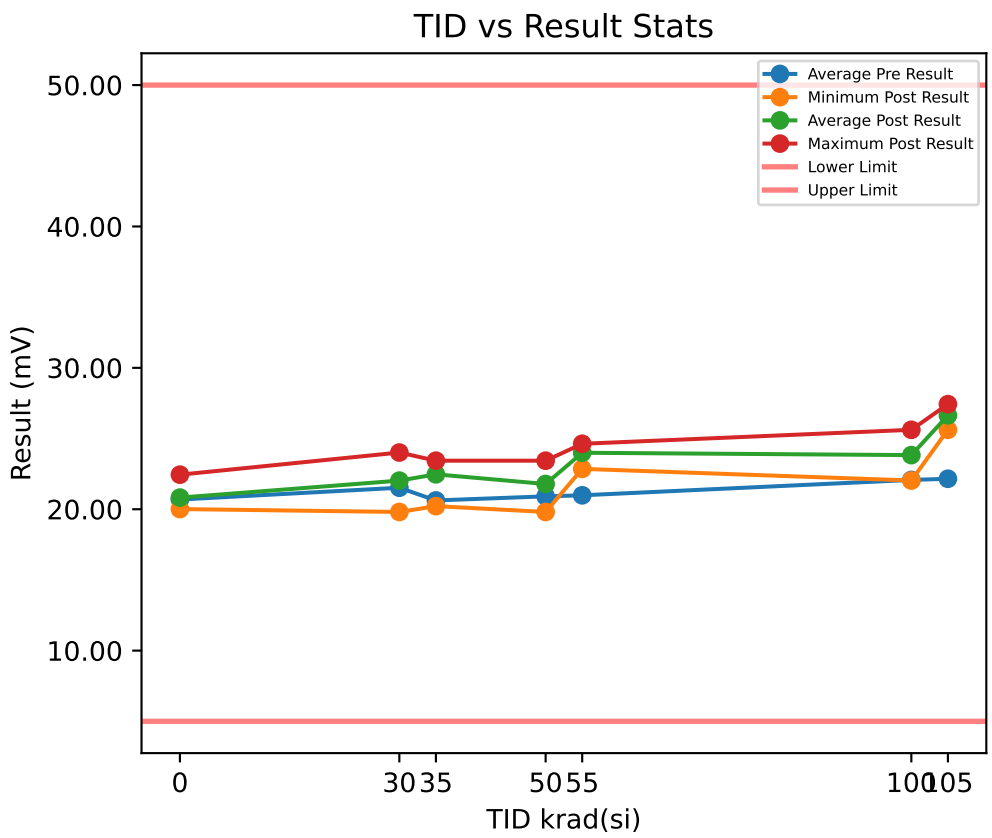
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

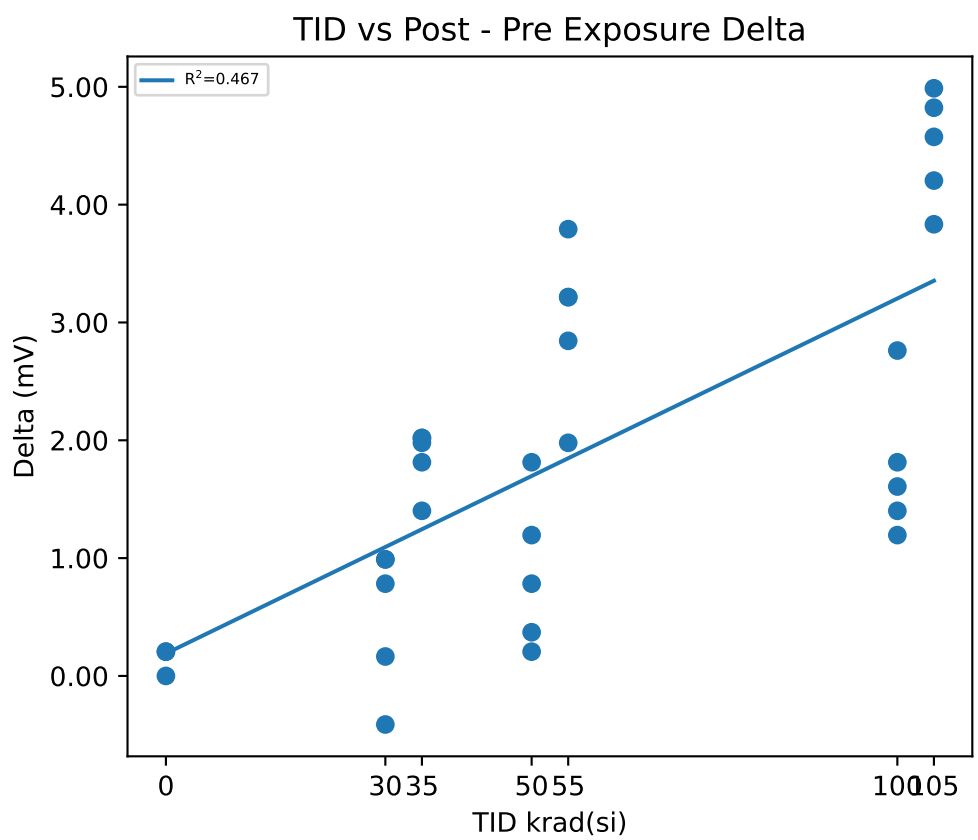
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.2995	2.3229	0.0234
2	0	CU2	2.2283	2.2501	0.0218
3	0	CU3	2.1715	2.1932	0.0217
11	30	Unbiased-30krad	2.2286	2.2516	0.023
12	30	Unbiased-30krad	2.2995	2.3244	0.0249
13	30	Unbiased-30krad	2.4201	2.4522	0.0321
14	30	Unbiased-30krad	2.2619	2.2889	0.027
15	30	Unbiased-30krad	2.2369	2.2633	0.0264
16	35	Biased-30krad	2.234	2.2637	0.0297
17	35	Biased-30krad	2.289	2.3198	0.0308
18	35	Biased-30krad	2.2692	2.2944	0.0252
19	35	Biased-30krad	2.3394	2.3719	0.0325
20	35	Biased-30krad	2.2602	2.2868	0.0266
30	50	Unbiased-50krad	2.2287	2.2526	0.0239
31	50	Unbiased-50krad	2.2084	2.2374	0.029
32	50	Unbiased-50krad	2.2543	2.2828	0.0285
33	50	Unbiased-50krad	2.198	2.2183	0.0203
34	50	Unbiased-50krad	2.2947	2.3261	0.0314
40	55	Biased-50krad	2.2535	2.2858	0.0323
41	55	Biased-50krad	2.1854	2.2185	0.0331
42	55	Biased-50krad	2.3512	2.3862	0.035
43	55	Biased-50krad	2.2318	2.2752	0.0434
44	55	Biased-50krad	2.0426	2.0765	0.0339
45	100	Unbiased-100krad	2.2198	2.2425	0.0227
46	100	Unbiased-100krad	2.0774	2.103	0.0256
47	100	Unbiased-100krad	2.2509	2.2737	0.0228
48	100	Unbiased-100krad	2.3595	2.3889	0.0294
49	100	Unbiased-100krad	2.231	2.2644	0.0334
50	105	Biased-100krad	2.3296	2.3799	0.0503
51	105	Biased-100krad	2.1408	2.1799	0.0391
52	105	Biased-100krad	2.1218	2.1597	0.0379
53	105	Biased-100krad	2.1058	2.1574	0.0516
54	105	Biased-100krad	2.2532	2.2843	0.0311

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1715	2.2331	2.2995	0.064135	2.1932	2.2554	2.3229	0.065012	0.0217	0.0223	0.0234	0.00095394
30	2.2286	2.2894	2.4201	0.078092	2.2516	2.3161	2.4522	0.081056	0.023	0.02668	0.0321	0.003401
35	2.234	2.2784	2.3394	0.039435	2.2637	2.3073	2.3719	0.041283	0.0252	0.02896	0.0325	0.0030072
50	2.198	2.2368	2.2947	0.038847	2.2183	2.2634	2.3261	0.042232	0.0203	0.02662	0.0314	0.004455
55	2.0426	2.2129	2.3512	0.11279	2.0765	2.2484	2.3862	0.11352	0.0323	0.03554	0.0434	0.0045059
100	2.0774	2.2277	2.3595	0.10071	2.103	2.2545	2.3889	0.10201	0.0227	0.02678	0.0334	0.004598
105	2.1058	2.1902	2.3296	0.09701	2.1574	2.2322	2.3799	0.097617	0.0311	0.042	0.0516	0.0087333

Device Test: 40.10 _SoftStart|MaxStartupVoltage/SS2/3/3///90.9/634//0///@V_SS_START





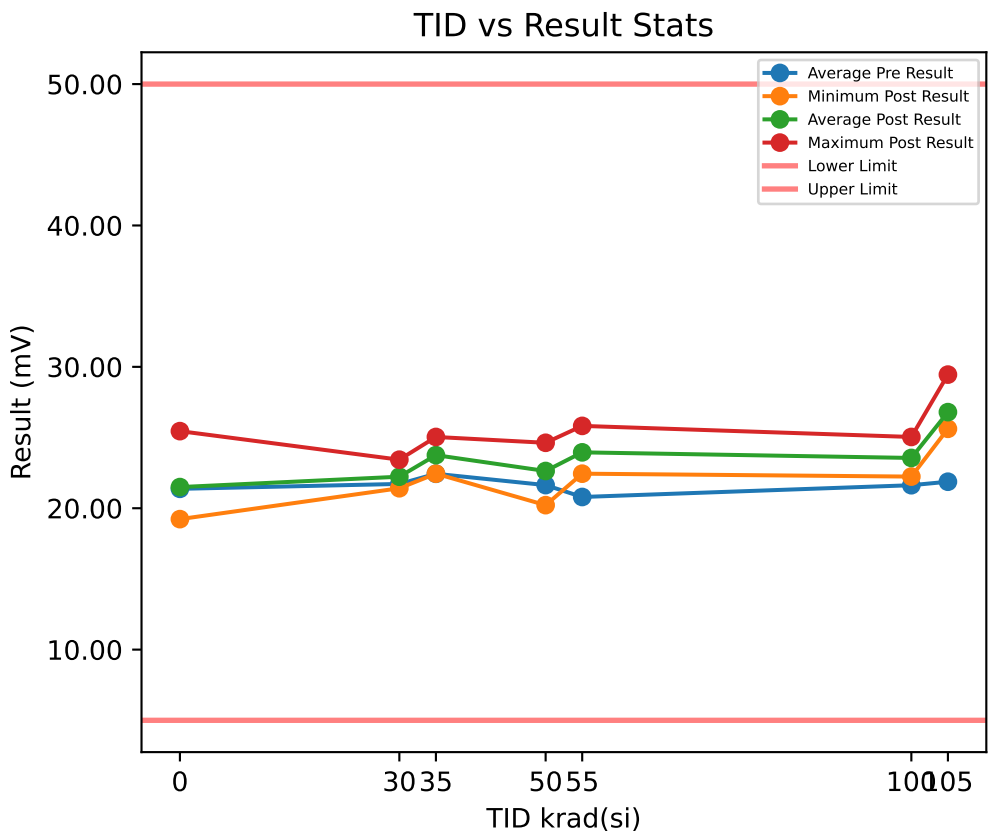
Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

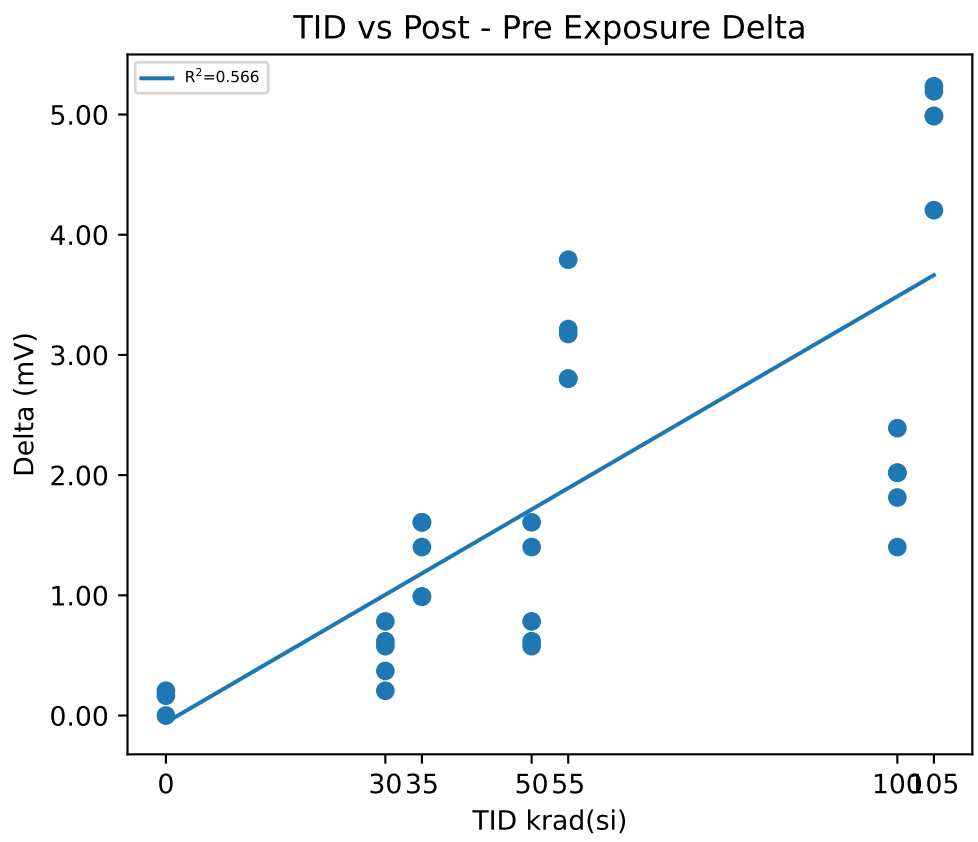
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	20.012	20.012	0
2	0	CU2	22.238	22.444	0.2061
3	0	CU3	19.806	20.012	0.2061
11	30	Unbiased-30krad	22.65	22.238	-0.4122
12	30	Unbiased-30krad	21.249	22.238	0.9892
13	30	Unbiased-30krad	19.641	19.806	0.1649
14	30	Unbiased-30krad	21.043	21.826	0.7831
15	30	Unbiased-30krad	23.021	24.011	0.9893
16	35	Biased-30krad	18.198	20.218	2.0198
17	35	Biased-30krad	21.043	23.021	1.9785
18	35	Biased-30krad	22.032	23.433	1.4015
19	35	Biased-30krad	20.424	22.444	2.0197
20	35	Biased-30krad	21.414	23.227	1.8137
30	50	Unbiased-50krad	22.65	23.433	0.7832
31	50	Unbiased-50krad	19.806	21.62	1.8136
32	50	Unbiased-50krad	21.043	22.238	1.1953
33	50	Unbiased-50krad	19.435	19.806	0.371
34	50	Unbiased-50krad	21.62	21.826	0.2061
40	55	Biased-50krad	20.012	22.856	2.8441
41	55	Biased-50krad	20.631	24.423	3.7922
42	55	Biased-50krad	21.414	24.629	3.2152
43	55	Biased-50krad	20.424	23.64	3.2151
44	55	Biased-50krad	22.444	24.423	1.9786
45	100	Unbiased-100krad	22.856	25.618	2.7617
46	100	Unbiased-100krad	20.631	22.032	1.4014
47	100	Unbiased-100krad	23.433	24.629	1.1954
48	100	Unbiased-100krad	22.032	23.846	1.8137
49	100	Unbiased-100krad	21.414	23.021	1.6076
50	105	Biased-100krad	23.021	26.855	3.8334
51	105	Biased-100krad	22.238	26.442	4.2044
52	105	Biased-100krad	21.043	25.618	4.5753
53	105	Biased-100krad	22.444	27.432	4.9876
54	105	Biased-100krad	22.032	26.855	4.8227

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.806	20.685	22.238	1.3485	20.012	20.823	22.444	1.4041	0	0.1374	0.2061	0.11899
30	19.641	21.521	23.021	1.3567	19.806	22.024	24.011	1.4997	-0.4122	0.50286	0.9893	0.61303
35	18.198	20.622	22.032	1.4751	20.218	22.469	23.433	1.3111	1.4015	1.8466	2.0198	0.26294
50	19.435	20.911	22.65	1.3175	19.806	21.785	23.433	1.3103	0.2061	0.87384	1.8136	0.65066
55	20.012	20.985	22.444	0.96163	22.856	23.994	24.629	0.74003	1.9786	3.009	3.7922	0.66845
100	20.631	22.073	23.433	1.116	22.032	23.829	25.618	1.3895	1.1954	1.756	2.7617	0.60762
105	21.043	22.156	23.021	0.72338	25.618	26.64	27.432	0.67127	3.8334	4.4847	4.9876	0.46854

Device Test: 40.11 _SoftStart|MaxStartupVoltage/SS3/3/3///90.9/634//0///@V_SS_START





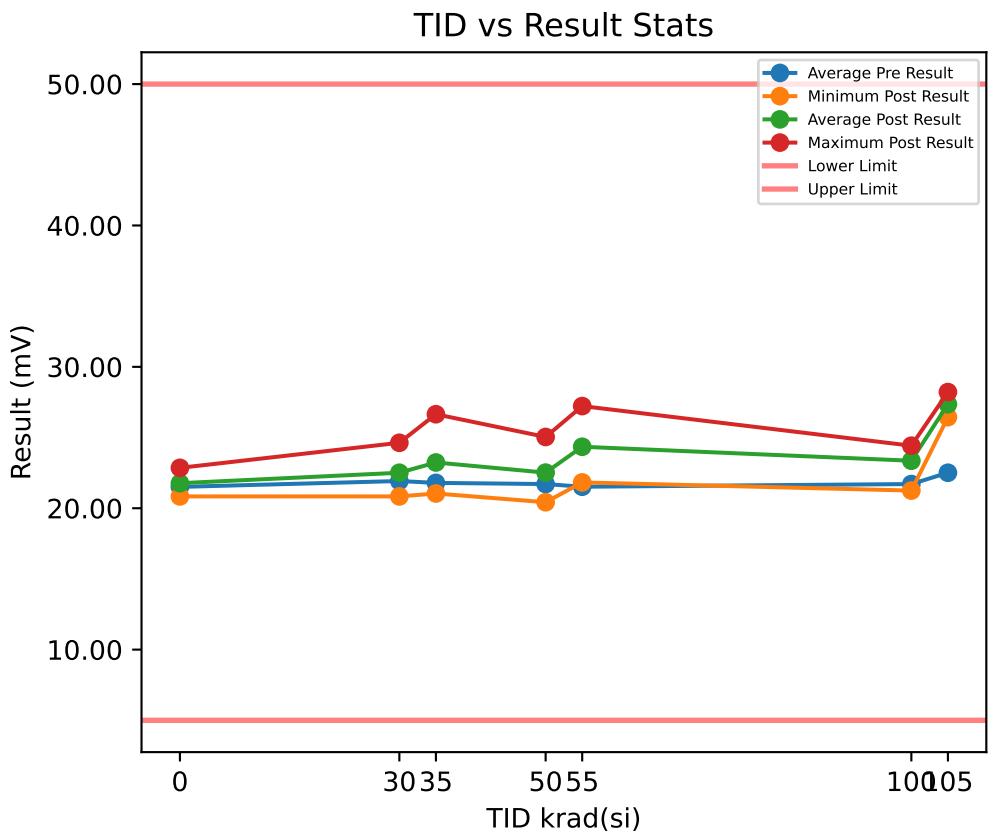
Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

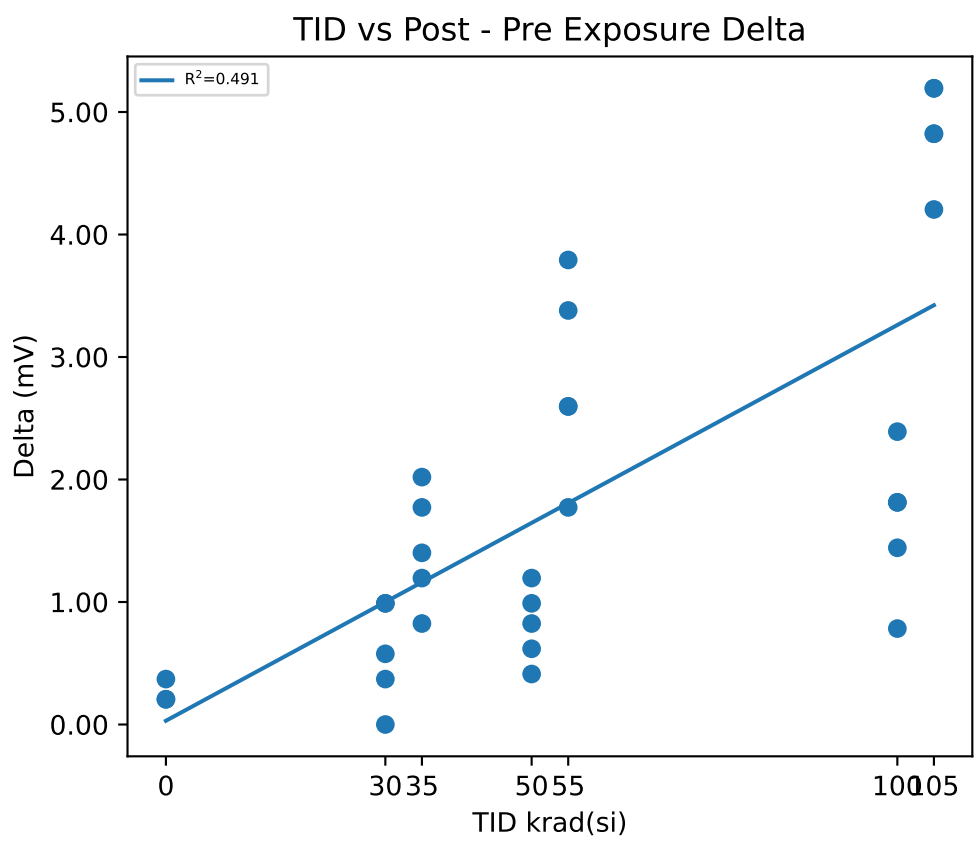
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	19.229	19.229	0
2	0	CU2	25.247	25.453	0.2061
3	0	CU3	19.641	19.806	0.1649
11	30	Unbiased-30krad	22.238	22.856	0.6183
12	30	Unbiased-30krad	21.826	22.032	0.2061
13	30	Unbiased-30krad	22.856	23.433	0.5771
14	30	Unbiased-30krad	20.631	21.414	0.7831
15	30	Unbiased-30krad	21.043	21.414	0.3709
16	35	Biased-30krad	20.837	22.444	1.6075
17	35	Biased-30krad	22.444	23.433	0.9893
18	35	Biased-30krad	23.021	24.011	0.9893
19	35	Biased-30krad	23.433	25.041	1.6076
20	35	Biased-30krad	22.444	23.846	1.4015
30	50	Unbiased-50krad	22.238	23.846	1.6076
31	50	Unbiased-50krad	19.641	20.218	0.5771
32	50	Unbiased-50krad	23.227	24.629	1.4015
33	50	Unbiased-50krad	21.249	22.032	0.7831
34	50	Unbiased-50krad	21.826	22.444	0.6183
40	55	Biased-50krad	23.021	25.824	2.8029
41	55	Biased-50krad	21.043	23.846	2.8029
42	55	Biased-50krad	19.229	22.444	3.2151
43	55	Biased-50krad	19.435	23.227	3.7922
44	55	Biased-50krad	21.249	24.423	3.1739
45	100	Unbiased-100krad	21.62	23.433	1.8137
46	100	Unbiased-100krad	22.65	25.041	2.3908
47	100	Unbiased-100krad	21.826	23.227	1.4015
48	100	Unbiased-100krad	21.826	23.846	2.0198
49	100	Unbiased-100krad	20.218	22.238	2.0197
50	105	Biased-100krad	21.043	26.03	4.9875
51	105	Biased-100krad	24.217	29.451	5.2349
52	105	Biased-100krad	20.631	25.824	5.1936
53	105	Biased-100krad	22.856	27.061	4.2044
54	105	Biased-100krad	20.631	25.618	4.9875

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.229	21.372	25.247	3.3619	19.229	21.496	25.453	3.4391	0	0.12367	0.2061	0.10906
30	20.631	21.719	22.856	0.89672	21.414	22.23	23.433	0.8962	0.2061	0.5111	0.7831	0.22501
35	20.837	22.436	23.433	0.98685	22.444	23.755	25.041	0.94196	0.9893	1.319	1.6076	0.31254
50	19.641	21.636	23.227	1.3285	20.218	22.634	24.629	1.7089	0.5771	0.99752	1.6076	0.47485
55	19.229	20.795	23.021	1.5431	22.444	23.953	25.824	1.2783	2.8029	3.1574	3.7922	0.40556
100	20.218	21.628	22.65	0.88183	22.238	23.557	25.041	1.0185	1.4015	1.9291	2.3908	0.361
105	20.631	21.875	24.217	1.5997	25.618	26.797	29.451	1.5843	4.2044	4.9216	5.2349	0.41689

Device Test: 40.12 _SoftStart|MaxStartupVoltage/SS4/3/3///90.9/634//0///@V_SS_START





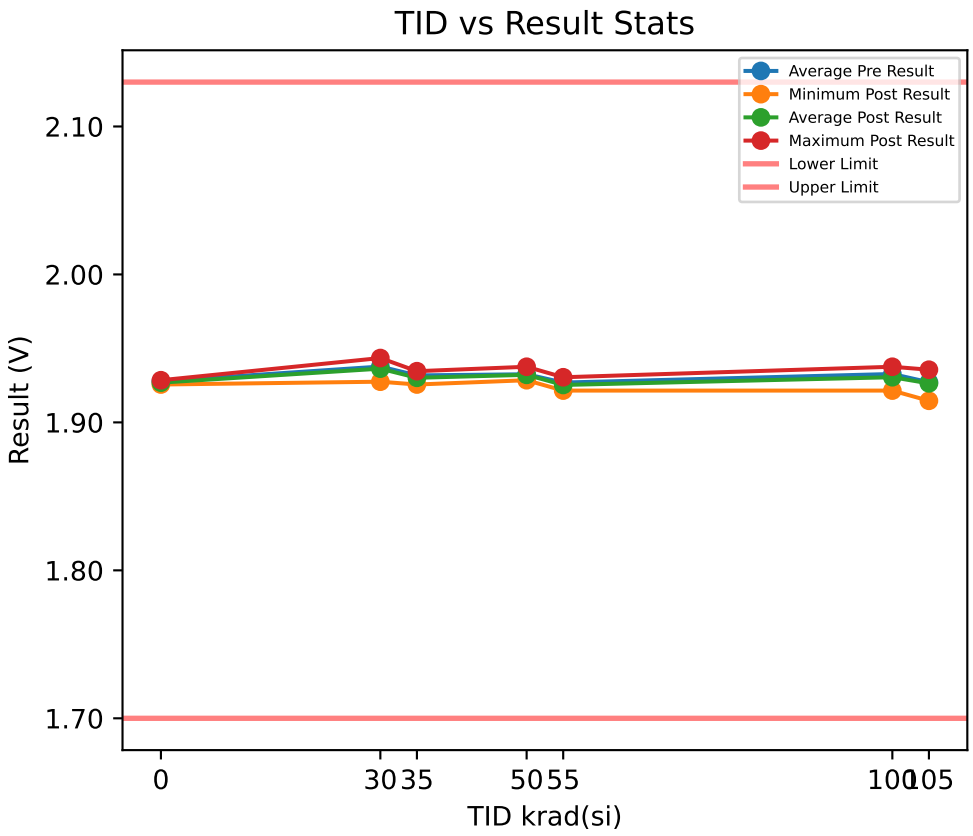
Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

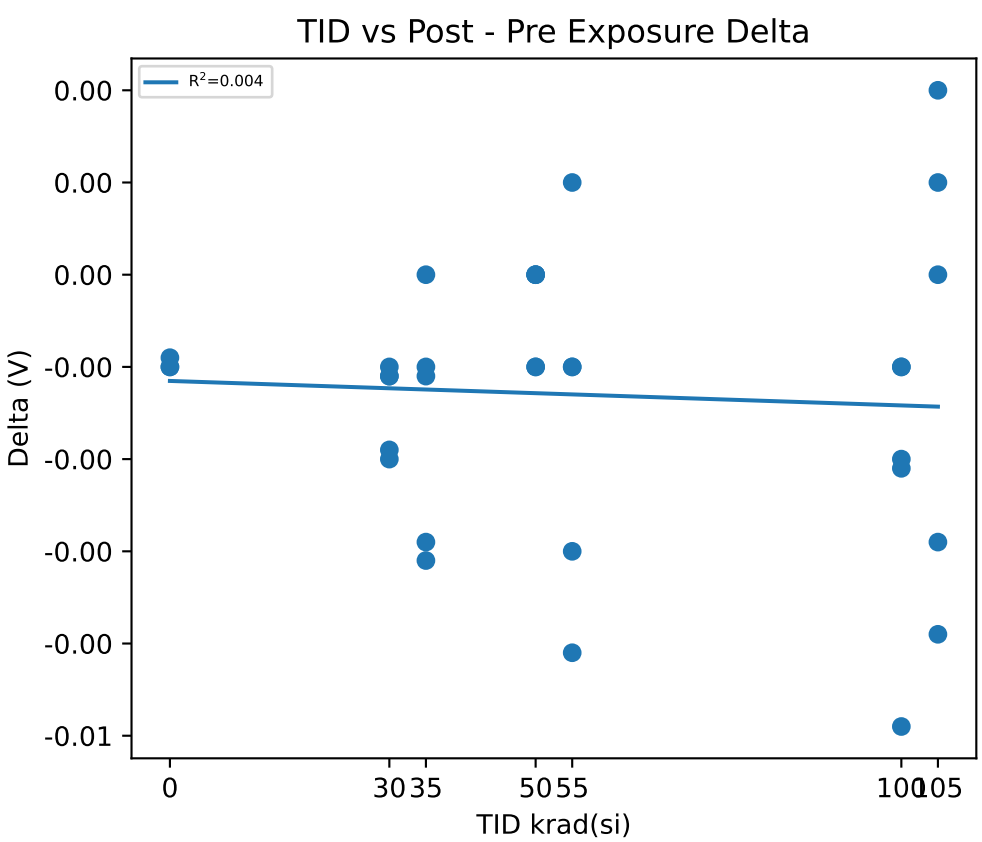
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	22.65	22.856	0.2061
2	0	CU2	21.249	21.62	0.3709
3	0	CU3	20.631	20.837	0.2061
11	30	Unbiased-30krad	21.043	22.032	0.9892
12	30	Unbiased-30krad	21.249	21.62	0.3709
13	30	Unbiased-30krad	22.856	23.433	0.5771
14	30	Unbiased-30krad	23.64	24.629	0.9893
15	30	Unbiased-30krad	20.837	20.837	0
16	35	Biased-30krad	21.826	23.227	1.4015
17	35	Biased-30krad	24.629	26.648	2.0197
18	35	Biased-30krad	20.218	21.043	0.8244
19	35	Biased-30krad	21.043	22.238	1.1953
20	35	Biased-30krad	21.249	23.021	1.7724
30	50	Unbiased-50krad	21.043	22.032	0.9892
31	50	Unbiased-50krad	19.229	20.424	1.1954
32	50	Unbiased-50krad	22.238	22.65	0.4122
33	50	Unbiased-50krad	24.423	25.041	0.6183
34	50	Unbiased-50krad	21.62	22.444	0.8244
40	55	Biased-50krad	21.249	23.021	1.7724
41	55	Biased-50krad	19.229	21.826	2.5968
42	55	Biased-50krad	23.846	27.226	3.38
43	55	Biased-50krad	22.65	25.247	2.5969
44	55	Biased-50krad	20.631	24.423	3.7922
45	100	Unbiased-100krad	22.856	23.64	0.7832
46	100	Unbiased-100krad	19.806	21.249	1.4427
47	100	Unbiased-100krad	22.032	24.423	2.3908
48	100	Unbiased-100krad	22.032	23.846	1.8137
49	100	Unbiased-100krad	21.826	23.64	1.8137
50	105	Biased-100krad	21.62	26.442	4.8227
51	105	Biased-100krad	23.846	28.05	4.2044
52	105	Biased-100krad	22.238	27.432	5.1937
53	105	Biased-100krad	23.021	28.215	5.1937
54	105	Biased-100krad	21.826	26.648	4.8227

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.631	21.51	22.65	1.0348	20.837	21.771	22.856	1.0183	0.2061	0.26103	0.3709	0.095147
30	20.837	21.925	23.64	1.2477	20.837	22.51	24.629	1.5136	0	0.5853	0.9893	0.42278
35	20.218	21.793	24.629	1.6868	21.043	23.236	26.648	2.0915	0.8244	1.4427	2.0197	0.47086
50	19.229	21.71	24.423	1.8872	20.424	22.518	25.041	1.6589	0.4122	0.8079	1.1954	0.30652
55	19.229	21.521	23.846	1.7888	21.826	24.348	27.226	2.0746	1.7724	2.8277	3.7922	0.78351
100	19.806	21.71	22.856	1.1357	21.249	23.359	24.423	1.2226	0.7832	1.6488	2.3908	0.59091
105	21.62	22.51	23.846	0.91923	26.442	27.357	28.215	0.80004	4.2044	4.8474	5.1937	0.40451

Device Test: 40.13 _SoftStart|ClampVoltage/COMP1/3/3///90.9/634//0///@COMP_V_CLAMP





Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

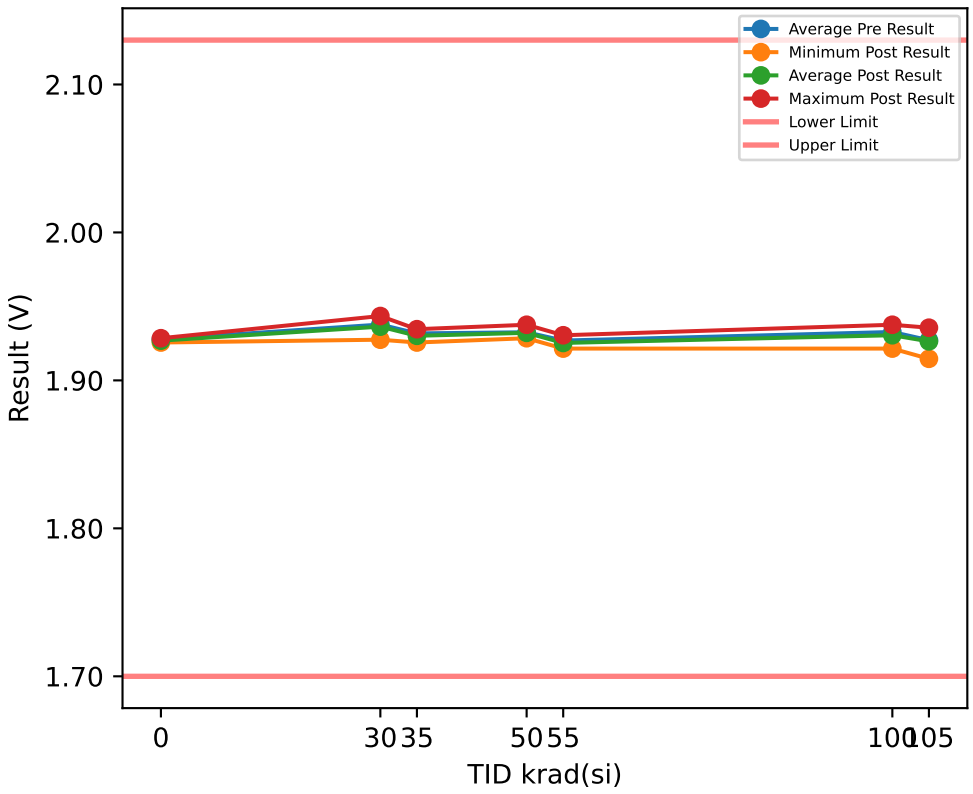
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9295	1.9285	-0.001
2	0	CU2	1.9265	1.9256	-0.0009
3	0	CU3	1.9275	1.9265	-0.001
11	30	Unbiased-30krad	1.9295	1.9275	-0.002
12	30	Unbiased-30krad	1.9336	1.9325	-0.0011
13	30	Unbiased-30krad	1.9446	1.9435	-0.0011
14	30	Unbiased-30krad	1.9395	1.9376	-0.0019
15	30	Unbiased-30krad	1.9415	1.9405	-0.001
16	35	Biased-30krad	1.9285	1.9256	-0.0029
17	35	Biased-30krad	1.9346	1.9346	0
18	35	Biased-30krad	1.9346	1.9315	-0.0031
19	35	Biased-30krad	1.9336	1.9325	-0.0011
20	35	Biased-30krad	1.9275	1.9265	-0.001
30	50	Unbiased-50krad	1.9285	1.9285	0
31	50	Unbiased-50krad	1.9376	1.9376	0
32	50	Unbiased-50krad	1.9315	1.9315	0
33	50	Unbiased-50krad	1.9295	1.9285	-0.001
34	50	Unbiased-50krad	1.9356	1.9346	-0.001
40	55	Biased-50krad	1.9315	1.9305	-0.001
41	55	Biased-50krad	1.9235	1.9225	-0.001
42	55	Biased-50krad	1.9265	1.9235	-0.003
43	55	Biased-50krad	1.9256	1.9215	-0.0041
44	55	Biased-50krad	1.9275	1.9285	0.001
45	100	Unbiased-100krad	1.9346	1.9325	-0.0021
46	100	Unbiased-100krad	1.9225	1.9215	-0.001
47	100	Unbiased-100krad	1.9425	1.9376	-0.0049
48	100	Unbiased-100krad	1.9315	1.9295	-0.002
49	100	Unbiased-100krad	1.9325	1.9315	-0.001
50	105	Biased-100krad	1.9336	1.9356	0.002
51	105	Biased-100krad	1.9295	1.9256	-0.0039
52	105	Biased-100krad	1.9275	1.9246	-0.0029
53	105	Biased-100krad	1.9146	1.9146	0
54	105	Biased-100krad	1.9305	1.9315	0.001

Test Statistics (V)

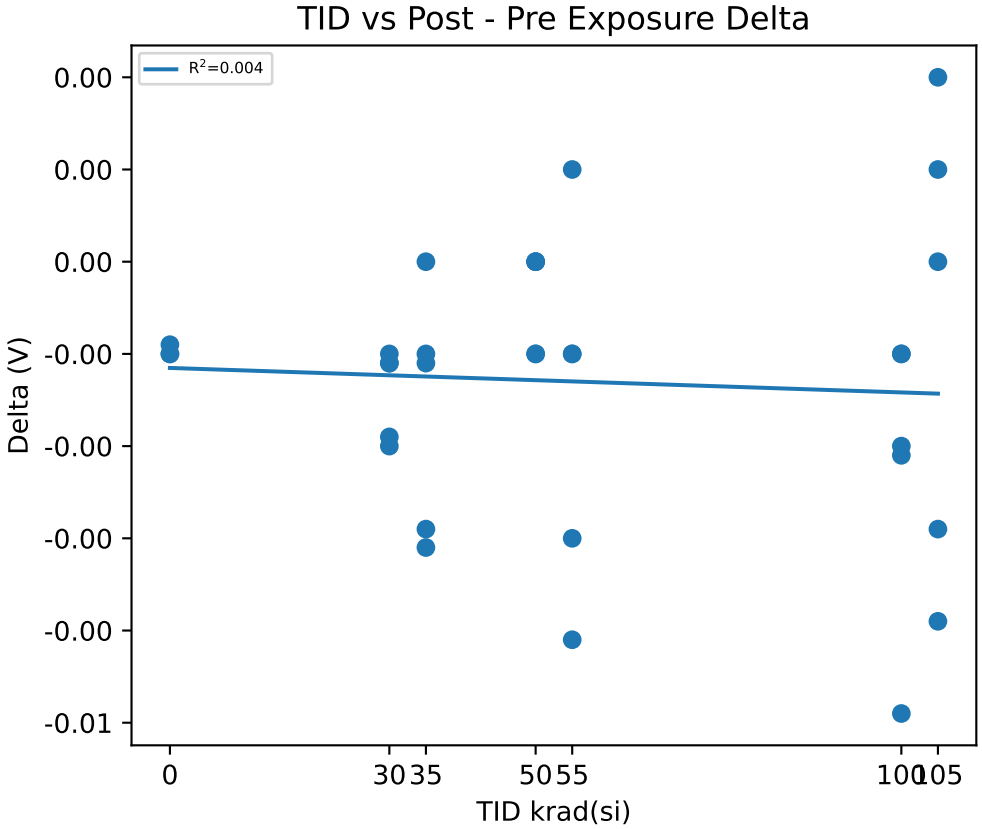
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9265	1.9278	1.9295	0.0015275	1.9256	1.9269	1.9285	0.0014844	-0.001	-0.00096667	-0.0009	5.7735e-05
30	1.9295	1.9377	1.9446	0.0061101	1.9275	1.9363	1.9435	0.0063845	-0.002	-0.00142	-0.001	0.00048683
35	1.9275	1.9318	1.9346	0.0034746	1.9256	1.9301	1.9346	0.0039106	-0.0031	-0.00162	0	0.001333
50	1.9285	1.9325	1.9376	0.0039247	1.9285	1.9321	1.9376	0.0039614	-0.001	-0.0004	0	0.00054772
55	1.9235	1.9269	1.9315	0.002955	1.9215	1.9253	1.9305	0.0039623	-0.0041	-0.00162	0.001	0.0019804
100	1.9225	1.9327	1.9425	0.0071618	1.9215	1.9305	1.9376	0.0058611	-0.0049	-0.0022	-0.001	0.0015984
105	1.9146	1.9271	1.9336	0.007348	1.9146	1.9264	1.9356	0.007965	-0.0039	-0.00076	0.002	0.0025363

Device Test: 40.14 _SoftStart|ClampVoltage/COMP2/3/3///90.9/634//0///@COMP_V_CLAMP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



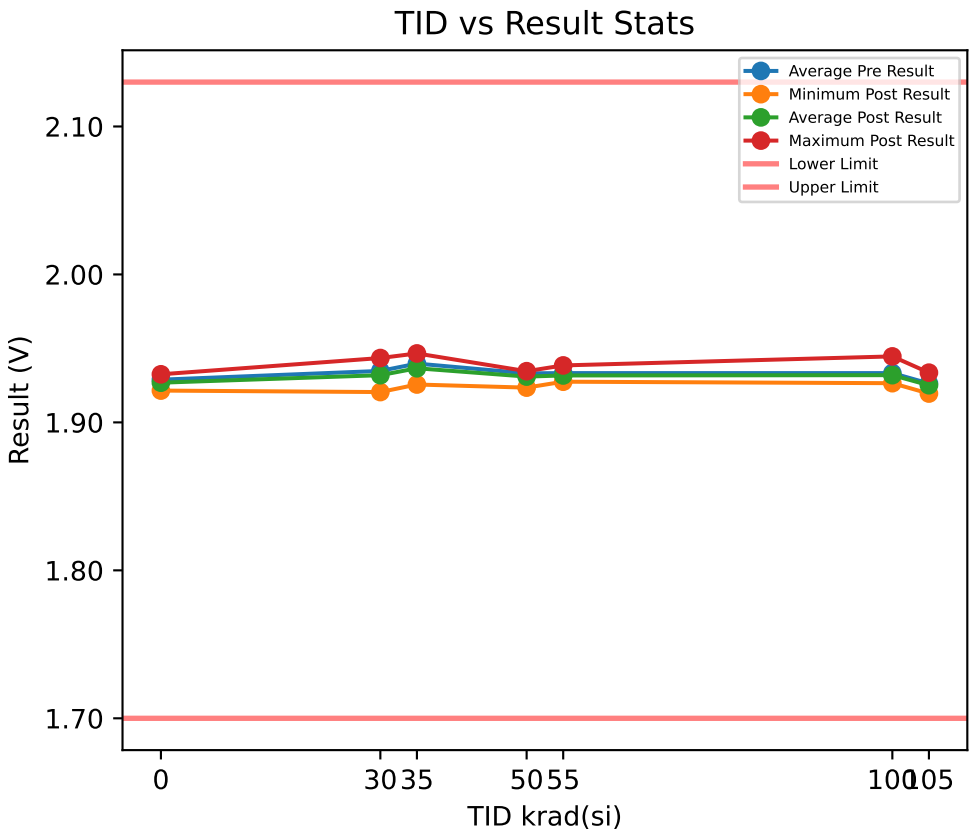
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

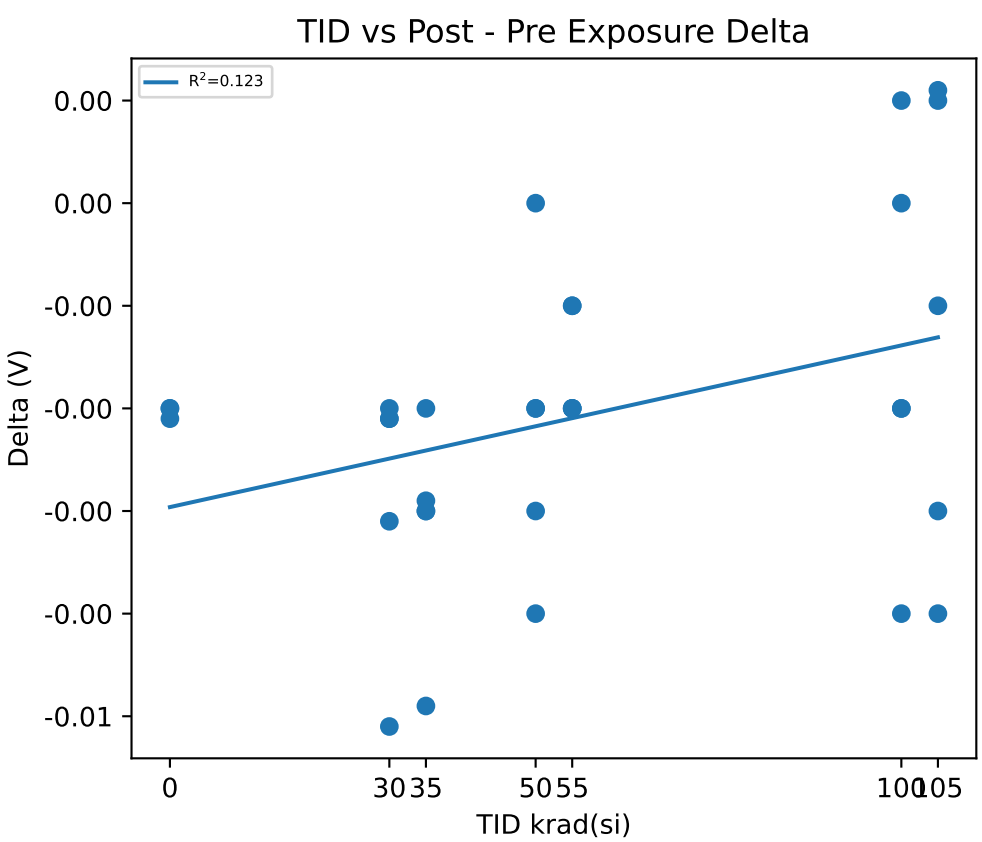
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9295	1.9285	-0.001
2	0	CU2	1.9265	1.9256	-0.0009
3	0	CU3	1.9275	1.9265	-0.001
11	30	Unbiased-30krad	1.9295	1.9275	-0.002
12	30	Unbiased-30krad	1.9336	1.9325	-0.0011
13	30	Unbiased-30krad	1.9446	1.9435	-0.0011
14	30	Unbiased-30krad	1.9395	1.9376	-0.0019
15	30	Unbiased-30krad	1.9415	1.9405	-0.001
16	35	Biased-30krad	1.9285	1.9256	-0.0029
17	35	Biased-30krad	1.9346	1.9346	0
18	35	Biased-30krad	1.9346	1.9315	-0.0031
19	35	Biased-30krad	1.9336	1.9325	-0.0011
20	35	Biased-30krad	1.9275	1.9265	-0.001
30	50	Unbiased-50krad	1.9285	1.9285	0
31	50	Unbiased-50krad	1.9376	1.9376	0
32	50	Unbiased-50krad	1.9315	1.9315	0
33	50	Unbiased-50krad	1.9295	1.9285	-0.001
34	50	Unbiased-50krad	1.9356	1.9346	-0.001
40	55	Biased-50krad	1.9315	1.9305	-0.001
41	55	Biased-50krad	1.9235	1.9225	-0.001
42	55	Biased-50krad	1.9265	1.9235	-0.003
43	55	Biased-50krad	1.9256	1.9215	-0.0041
44	55	Biased-50krad	1.9275	1.9285	0.001
45	100	Unbiased-100krad	1.9346	1.9325	-0.0021
46	100	Unbiased-100krad	1.9225	1.9215	-0.001
47	100	Unbiased-100krad	1.9425	1.9376	-0.0049
48	100	Unbiased-100krad	1.9315	1.9295	-0.002
49	100	Unbiased-100krad	1.9325	1.9315	-0.001
50	105	Biased-100krad	1.9336	1.9356	0.002
51	105	Biased-100krad	1.9295	1.9256	-0.0039
52	105	Biased-100krad	1.9275	1.9246	-0.0029
53	105	Biased-100krad	1.9146	1.9146	0
54	105	Biased-100krad	1.9305	1.9315	0.001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9265	1.9278	1.9295	0.0015275	1.9256	1.9269	1.9285	0.0014844	-0.001	-0.00096667	-0.0009	5.7735e-05
30	1.9295	1.9377	1.9446	0.0061101	1.9275	1.9363	1.9435	0.0063845	-0.002	-0.00142	-0.001	0.00048683
35	1.9275	1.9318	1.9346	0.0034746	1.9256	1.9301	1.9346	0.0039106	-0.0031	-0.00162	0	0.001333
50	1.9285	1.9325	1.9376	0.0039247	1.9285	1.9321	1.9376	0.0039614	-0.001	-0.0004	0	0.00054772
55	1.9235	1.9269	1.9315	0.002955	1.9215	1.9253	1.9305	0.0039623	-0.0041	-0.00162	0.001	0.0019804
100	1.9225	1.9327	1.9425	0.0071618	1.9215	1.9305	1.9376	0.0058611	-0.0049	-0.0022	-0.001	0.0015984
105	1.9146	1.9271	1.9336	0.007348	1.9146	1.9264	1.9356	0.007965	-0.0039	-0.00076	0.002	0.0025363

Device Test: 40.15 _SoftStart|ClampVoltage/COMP3/3/3///90.9/634//0///@COMP_V_CLAMP





Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

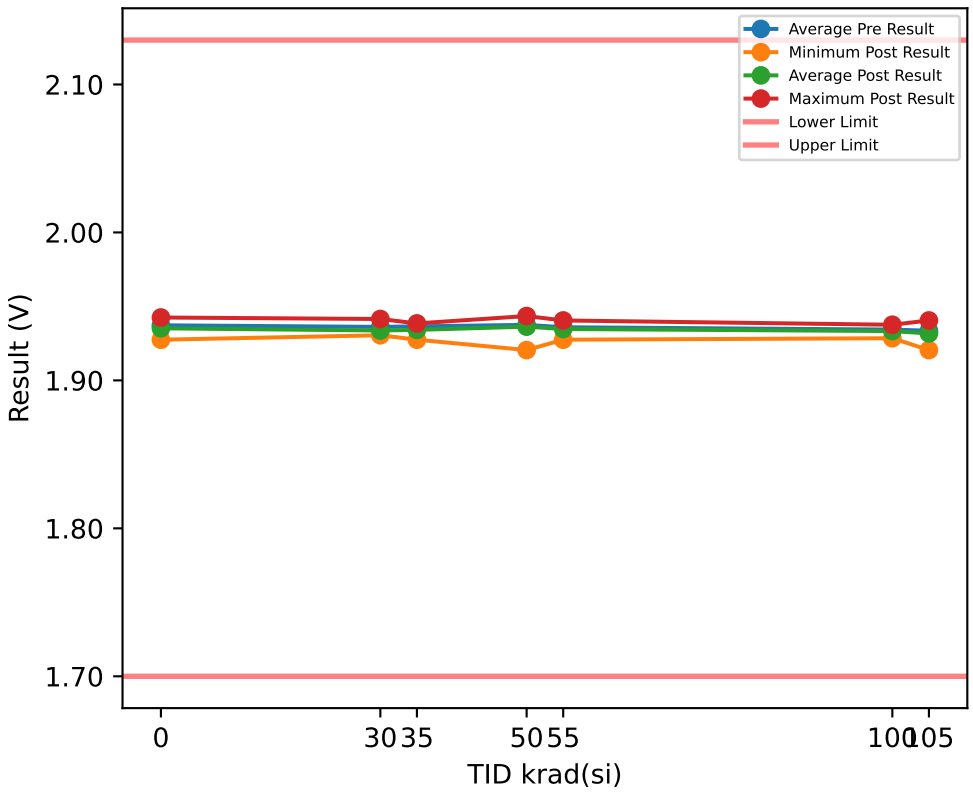
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9346	1.9325	-0.0021
2	0	CU2	1.9235	1.9215	-0.002
3	0	CU3	1.9285	1.9265	-0.002
11	30	Unbiased-30krad	1.9256	1.9225	-0.0031
12	30	Unbiased-30krad	1.9466	1.9415	-0.0051
13	30	Unbiased-30krad	1.9456	1.9435	-0.0021
14	30	Unbiased-30krad	1.9336	1.9315	-0.0021
15	30	Unbiased-30krad	1.9225	1.9205	-0.002
16	35	Biased-30krad	1.9285	1.9256	-0.0029
17	35	Biased-30krad	1.9435	1.9405	-0.003
18	35	Biased-30krad	1.9405	1.9356	-0.0049
19	35	Biased-30krad	1.9486	1.9466	-0.002
20	35	Biased-30krad	1.9376	1.9346	-0.003
30	50	Unbiased-50krad	1.9366	1.9346	-0.002
31	50	Unbiased-50krad	1.9366	1.9336	-0.003
32	50	Unbiased-50krad	1.9285	1.9285	0
33	50	Unbiased-50krad	1.9275	1.9235	-0.004
34	50	Unbiased-50krad	1.9366	1.9346	-0.002
40	55	Biased-50krad	1.9305	1.9285	-0.002
41	55	Biased-50krad	1.9395	1.9385	-0.001
42	55	Biased-50krad	1.9295	1.9275	-0.002
43	55	Biased-50krad	1.9295	1.9275	-0.002
44	55	Biased-50krad	1.9376	1.9366	-0.001
45	100	Unbiased-100krad	1.9305	1.9265	-0.004
46	100	Unbiased-100krad	1.9295	1.9305	0.001
47	100	Unbiased-100krad	1.9466	1.9446	-0.002
48	100	Unbiased-100krad	1.9315	1.9315	0
49	100	Unbiased-100krad	1.9285	1.9265	-0.002
50	105	Biased-100krad	1.9305	1.9315	0.001
51	105	Biased-100krad	1.9225	1.9215	-0.001
52	105	Biased-100krad	1.9325	1.9336	0.0011
53	105	Biased-100krad	1.9235	1.9195	-0.004
54	105	Biased-100krad	1.9225	1.9195	-0.003

Test Statistics (V)

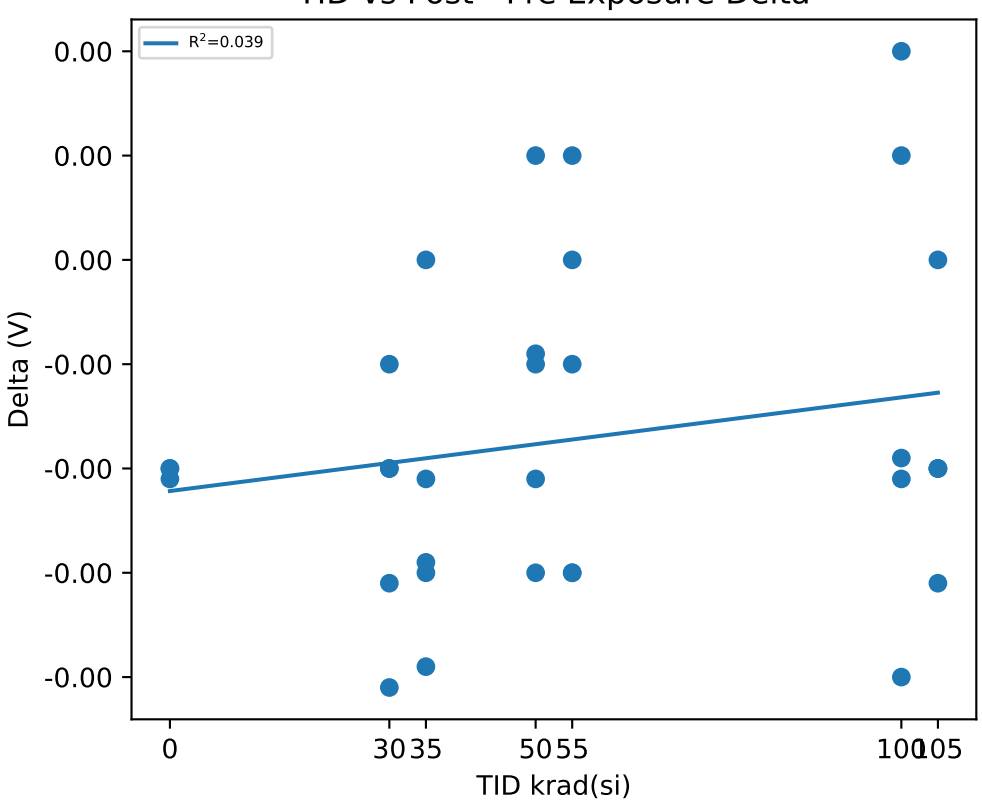
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9235	1.9289	1.9346	0.0055591	1.9215	1.9268	1.9325	0.0055076	-0.0021	-0.0020333	-0.002	5.7735e-05
30	1.9225	1.9348	1.9466	0.011105	1.9205	1.9319	1.9435	0.01055	-0.0051	-0.00288	-0.002	0.0013198
35	1.9285	1.9397	1.9486	0.0074855	1.9256	1.9366	1.9466	0.0077654	-0.0049	-0.00316	-0.002	0.0010597
50	1.9275	1.9332	1.9366	0.0047237	1.9235	1.931	1.9346	0.0048778	-0.004	-0.0022	0	0.0014832
55	1.9295	1.9333	1.9395	0.0048386	1.9275	1.9317	1.9385	0.0053798	-0.002	-0.0016	-0.001	0.00054772
100	1.9285	1.9333	1.9466	0.0075075	1.9265	1.9319	1.9446	0.0074453	-0.004	-0.0014	0.001	0.0019494
105	1.9225	1.9263	1.9325	0.0048166	1.9195	1.9251	1.9336	0.0068718	-0.004	-0.00118	0.0011	0.0023048

Device Test: 40.16 _SoftStart|ClampVoltage/COMP4/3/3///90.9/634//0///@COMP_V_CLAMP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



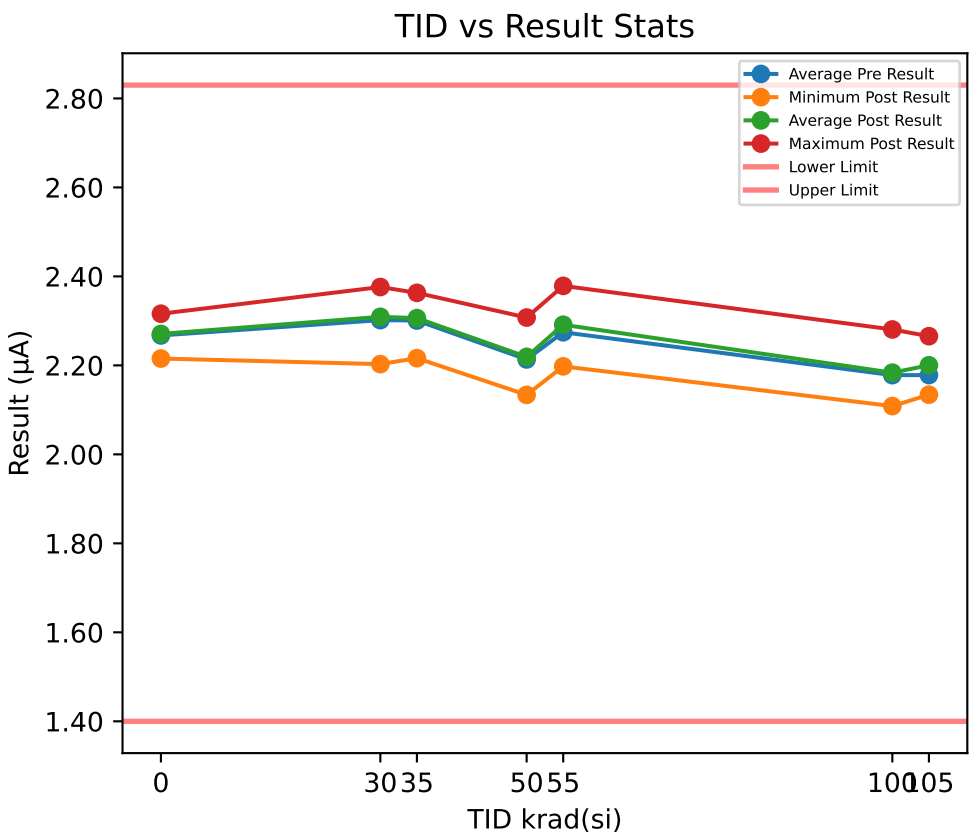
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

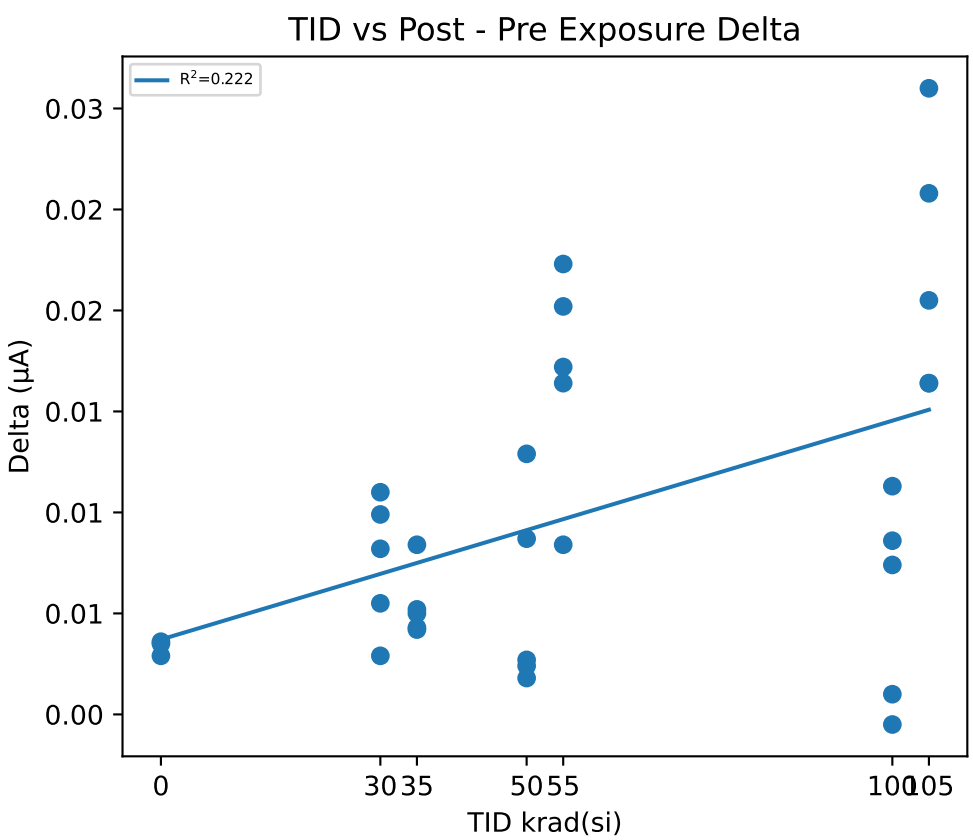
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9446	1.9425	-0.0021
2	0	CU2	1.9295	1.9275	-0.002
3	0	CU3	1.9376	1.9356	-0.002
11	30	Unbiased-30krad	1.9366	1.9325	-0.0041
12	30	Unbiased-30krad	1.9325	1.9305	-0.002
13	30	Unbiased-30krad	1.9446	1.9415	-0.0031
14	30	Unbiased-30krad	1.9356	1.9336	-0.002
15	30	Unbiased-30krad	1.9315	1.9305	-0.001
16	35	Biased-30krad	1.9385	1.9356	-0.0029
17	35	Biased-30krad	1.9415	1.9385	-0.003
18	35	Biased-30krad	1.9346	1.9325	-0.0021
19	35	Biased-30krad	1.9405	1.9366	-0.0039
20	35	Biased-30krad	1.9275	1.9275	0
30	50	Unbiased-50krad	1.9235	1.9205	-0.003
31	50	Unbiased-50krad	1.9405	1.9415	0.001
32	50	Unbiased-50krad	1.9385	1.9376	-0.0009
33	50	Unbiased-50krad	1.9456	1.9435	-0.0021
34	50	Unbiased-50krad	1.9395	1.9385	-0.001
40	55	Biased-50krad	1.9346	1.9336	-0.001
41	55	Biased-50krad	1.9325	1.9325	0
42	55	Biased-50krad	1.9395	1.9405	0.001
43	55	Biased-50krad	1.9305	1.9275	-0.003
44	55	Biased-50krad	1.9425	1.9395	-0.003
45	100	Unbiased-100krad	1.9346	1.9325	-0.0021
46	100	Unbiased-100krad	1.9315	1.9325	0.001
47	100	Unbiased-100krad	1.9325	1.9285	-0.004
48	100	Unbiased-100krad	1.9336	1.9356	0.002
49	100	Unbiased-100krad	1.9395	1.9376	-0.0019
50	105	Biased-100krad	1.9376	1.9356	-0.002
51	105	Biased-100krad	1.9425	1.9405	-0.002
52	105	Biased-100krad	1.9225	1.9205	-0.002
53	105	Biased-100krad	1.9315	1.9315	0
54	105	Biased-100krad	1.9336	1.9305	-0.0031

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9295	1.9372	1.9446	0.0075567	1.9275	1.9352	1.9425	0.007508	-0.0021	-0.0020333	-0.002	5.7735e-05
30	1.9315	1.9362	1.9446	0.0051685	1.9305	1.9337	1.9415	0.0045488	-0.0041	-0.00244	-0.001	0.0011887
35	1.9275	1.9365	1.9415	0.0056923	1.9275	1.9341	1.9385	0.0043003	-0.0039	-0.00238	0	0.0014755
50	1.9235	1.9375	1.9456	0.0083007	1.9205	1.9363	1.9435	0.0091522	-0.003	-0.0012	0.001	0.0015017
55	1.9305	1.9359	1.9425	0.0049731	1.9275	1.9347	1.9405	0.0053518	-0.003	-0.0012	0.001	0.0017889
100	1.9315	1.9343	1.9395	0.0031101	1.9285	1.9333	1.9376	0.0034674	-0.004	-0.001	0.002	0.0024505
105	1.9225	1.9335	1.9425	0.0074634	1.9205	1.9317	1.9405	0.0074089	-0.0031	-0.00182	0	0.0011234

Device Test: 40.2 _SoftStart|ChargeCurrent/SS2/3/3///90.9/634//0///@I_SS





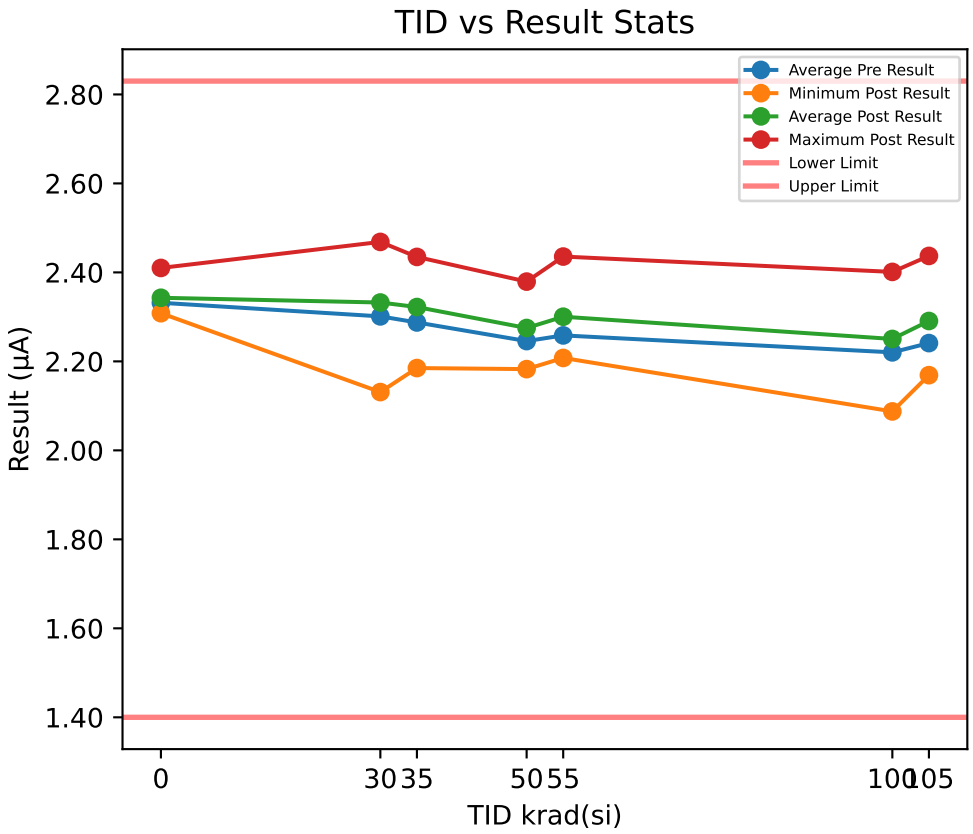
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

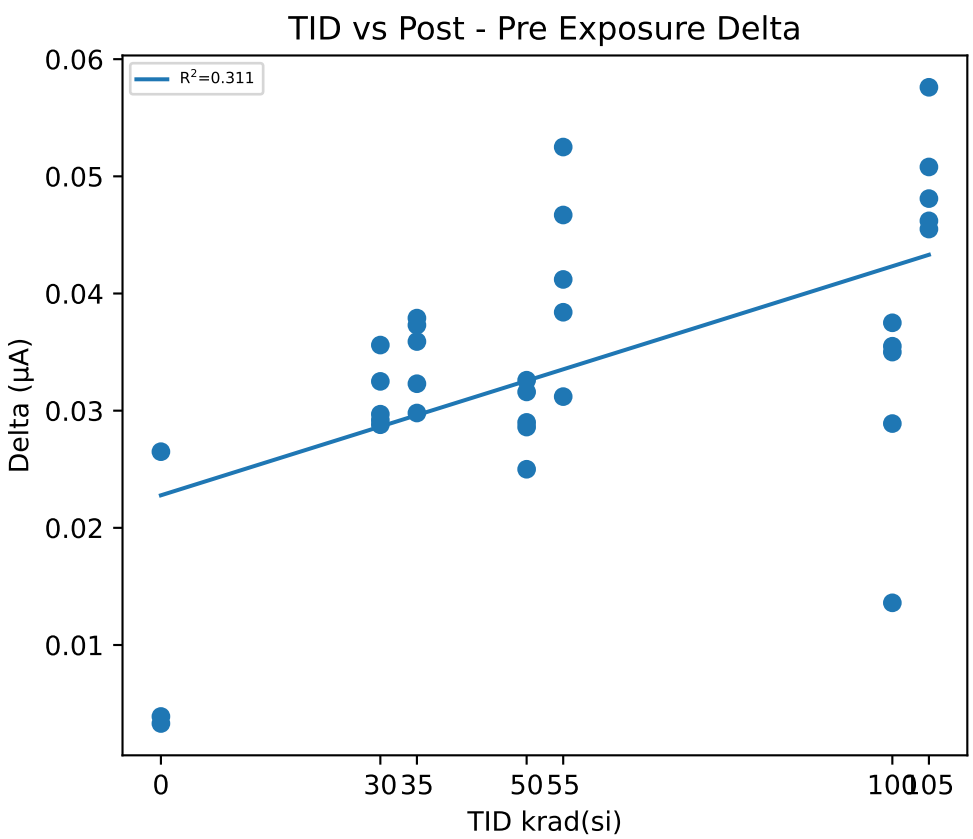
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3126	2.3161	0.0035
2	0	CU2	2.2118	2.2154	0.0036
3	0	CU3	2.2777	2.2806	0.0029
11	30	Unbiased-30krad	2.3474	2.3556	0.0082
12	30	Unbiased-30krad	2.3646	2.3675	0.0029
13	30	Unbiased-30krad	2.3651	2.3761	0.011
14	30	Unbiased-30krad	2.1973	2.2028	0.0055
15	30	Unbiased-30krad	2.234	2.2439	0.0099
16	35	Biased-30krad	2.3022	2.3106	0.0084
17	35	Biased-30krad	2.3511	2.3554	0.0043
18	35	Biased-30krad	2.2816	2.2858	0.0042
19	35	Biased-30krad	2.3578	2.363	0.0052
20	35	Biased-30krad	2.2112	2.2162	0.005
30	50	Unbiased-50krad	2.1847	2.1934	0.0087
31	50	Unbiased-50krad	2.3057	2.3075	0.0018
32	50	Unbiased-50krad	2.1745	2.1874	0.0129
33	50	Unbiased-50krad	2.1313	2.1337	0.0024
34	50	Unbiased-50krad	2.2708	2.2735	0.0027
40	55	Biased-50krad	2.2807	2.3009	0.0202
41	55	Biased-50krad	2.3426	2.351	0.0084
42	55	Biased-50krad	2.3623	2.3787	0.0164
43	55	Biased-50krad	2.206	2.2283	0.0223
44	55	Biased-50krad	2.1806	2.1978	0.0172
45	100	Unbiased-100krad	2.152	2.1515	-0.0005
46	100	Unbiased-100krad	2.0999	2.1085	0.0086
47	100	Unbiased-100krad	2.2041	2.2051	0.001
48	100	Unbiased-100krad	2.2733	2.2807	0.0074
49	100	Unbiased-100krad	2.1611	2.1724	0.0113
50	105	Biased-100krad	2.219	2.2354	0.0164
51	105	Biased-100krad	2.1329	2.1639	0.031
52	105	Biased-100krad	2.1856	2.202	0.0164
53	105	Biased-100krad	2.1083	2.1341	0.0258
54	105	Biased-100krad	2.2451	2.2656	0.0205

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2118	2.2674	2.3126	0.051188	2.2154	2.2707	2.3161	0.051075	0.0029	0.0033333	0.0036	0.00037859
30	2.1973	2.3017	2.3651	0.079917	2.2028	2.3092	2.3761	0.08002	0.0029	0.0075	0.011	0.0033038
35	2.2112	2.3008	2.3578	0.059535	2.2162	2.3062	2.363	0.059545	0.0042	0.00542	0.0084	0.001721
50	2.1313	2.2134	2.3057	0.072269	2.1337	2.2191	2.3075	0.070236	0.0018	0.0057	0.0129	0.0048974
55	2.1806	2.2744	2.3623	0.080459	2.1978	2.2913	2.3787	0.07747	0.0084	0.0169	0.0223	0.0053066
100	2.0999	2.1781	2.2733	0.064855	2.1085	2.1836	2.2807	0.064588	-0.0005	0.00556	0.0113	0.0050767
105	2.1083	2.1782	2.2451	0.0573	2.1341	2.2002	2.2656	0.05293	0.0164	0.02202	0.031	0.0063326

Device Test: 40.3 _SoftStart|ChargeCurrent/SS3/3/3///90.9/634//0///@I_SS





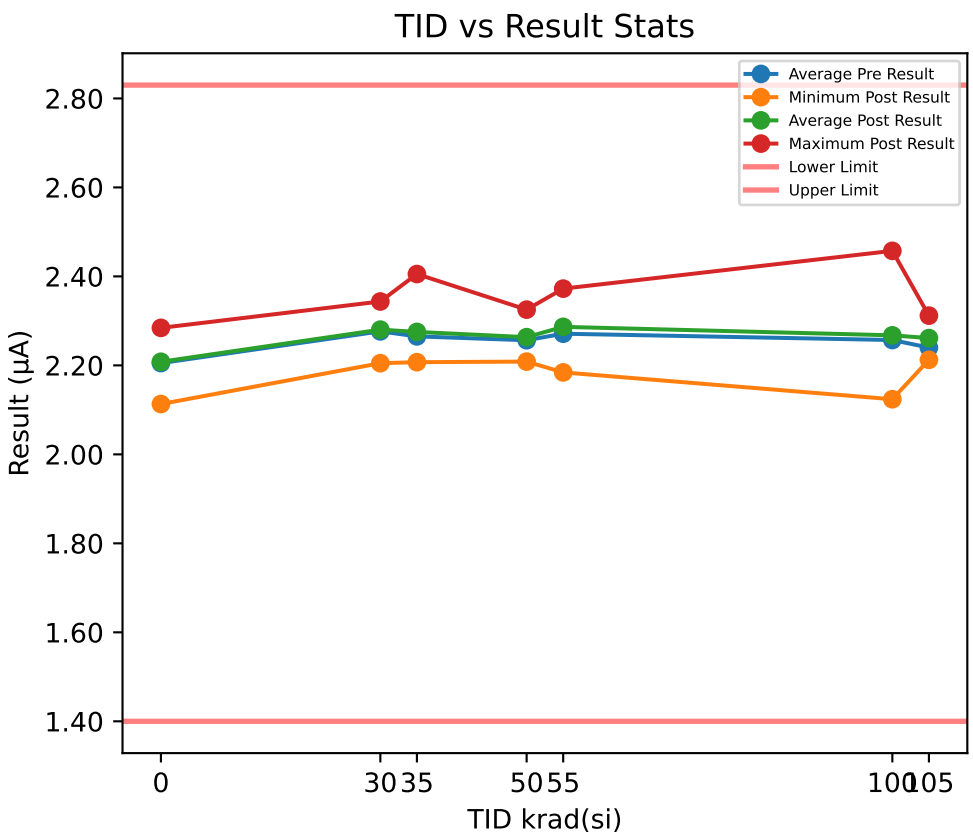
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

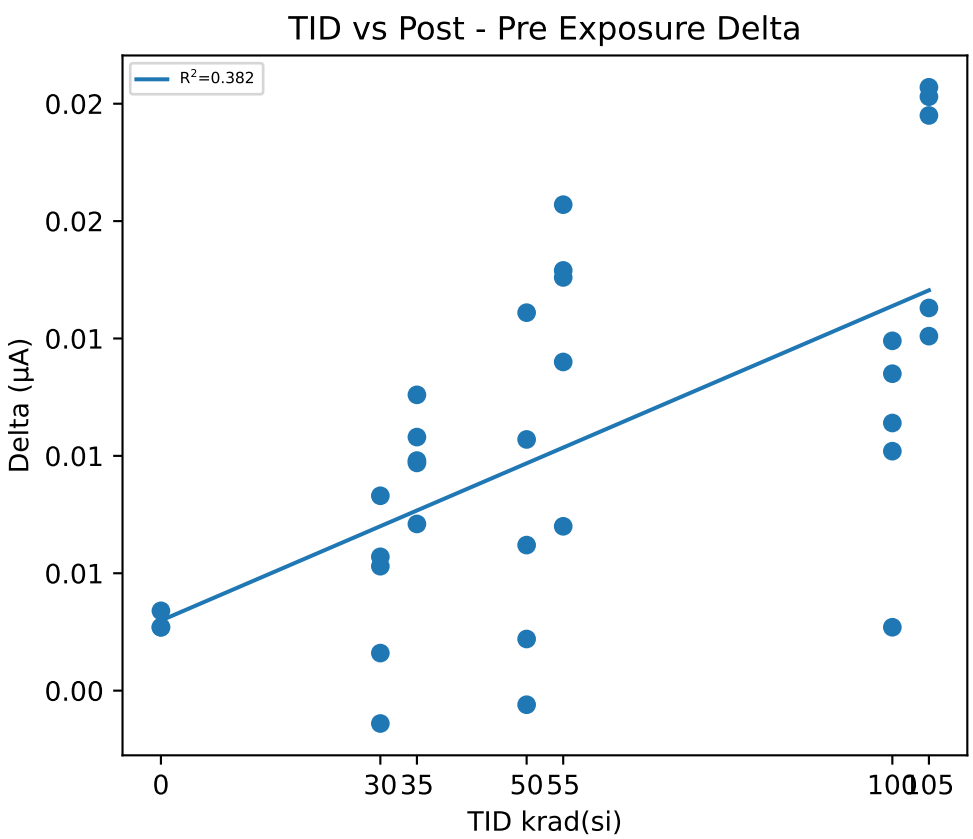
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4067	2.41	0.0033
2	0	CU2	2.3044	2.3083	0.0039
3	0	CU3	2.2841	2.3106	0.0265
11	30	Unbiased-30krad	2.299	2.3278	0.0288
12	30	Unbiased-30krad	2.3555	2.3847	0.0292
13	30	Unbiased-30krad	2.4329	2.4685	0.0356
14	30	Unbiased-30krad	2.0985	2.131	0.0325
15	30	Unbiased-30krad	2.3199	2.3496	0.0297
16	35	Biased-30krad	2.2638	2.2961	0.0323
17	35	Biased-30krad	2.3152	2.3531	0.0379
18	35	Biased-30krad	2.3119	2.3417	0.0298
19	35	Biased-30krad	2.3975	2.4348	0.0373
20	35	Biased-30krad	2.1491	2.185	0.0359
30	50	Unbiased-50krad	2.154	2.1826	0.0286
31	50	Unbiased-50krad	2.1851	2.2101	0.025
32	50	Unbiased-50krad	2.245	2.274	0.029
33	50	Unbiased-50krad	2.3477	2.3793	0.0316
34	50	Unbiased-50krad	2.2964	2.329	0.0326
40	55	Biased-50krad	2.2982	2.3294	0.0312
41	55	Biased-50krad	2.2426	2.281	0.0384
42	55	Biased-50krad	2.3831	2.4356	0.0525
43	55	Biased-50krad	2.161	2.2077	0.0467
44	55	Biased-50krad	2.207	2.2482	0.0412
45	100	Unbiased-100krad	2.1807	2.2096	0.0289
46	100	Unbiased-100krad	2.0739	2.0875	0.0136
47	100	Unbiased-100krad	2.2225	2.2575	0.035
48	100	Unbiased-100krad	2.3656	2.4011	0.0355
49	100	Unbiased-100krad	2.2588	2.2963	0.0375
50	105	Biased-100krad	2.3915	2.437	0.0455
51	105	Biased-100krad	2.1636	2.2117	0.0481
52	105	Biased-100krad	2.2637	2.3213	0.0576
53	105	Biased-100krad	2.1182	2.169	0.0508
54	105	Biased-100krad	2.2686	2.3148	0.0462

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2841	2.3317	2.4067	0.065712	2.3083	2.343	2.41	0.058064	0.0033	0.011233	0.0265	0.013225
30	2.0985	2.3012	2.4329	0.12423	2.131	2.3323	2.4685	0.12464	0.0288	0.03116	0.0356	0.0028745
35	2.1491	2.2875	2.3975	0.091075	2.185	2.3221	2.4348	0.091541	0.0298	0.03464	0.0379	0.003471
50	2.154	2.2456	2.3477	0.079146	2.1826	2.275	2.3793	0.081464	0.025	0.02936	0.0326	0.0029678
55	2.161	2.2584	2.3831	0.085896	2.2077	2.3004	2.4356	0.08777	0.0312	0.042	0.0525	0.0081022
100	2.0739	2.2203	2.3656	0.10677	2.0875	2.2504	2.4011	0.11518	0.0136	0.0301	0.0375	0.0097675
105	2.1182	2.2411	2.3915	0.10606	2.169	2.2908	2.437	0.10485	0.0455	0.04964	0.0576	0.0049003

Device Test: 40.4 _SoftStart|ChargeCurrent/SS4/3/3///90.9/634//0///@I_SS





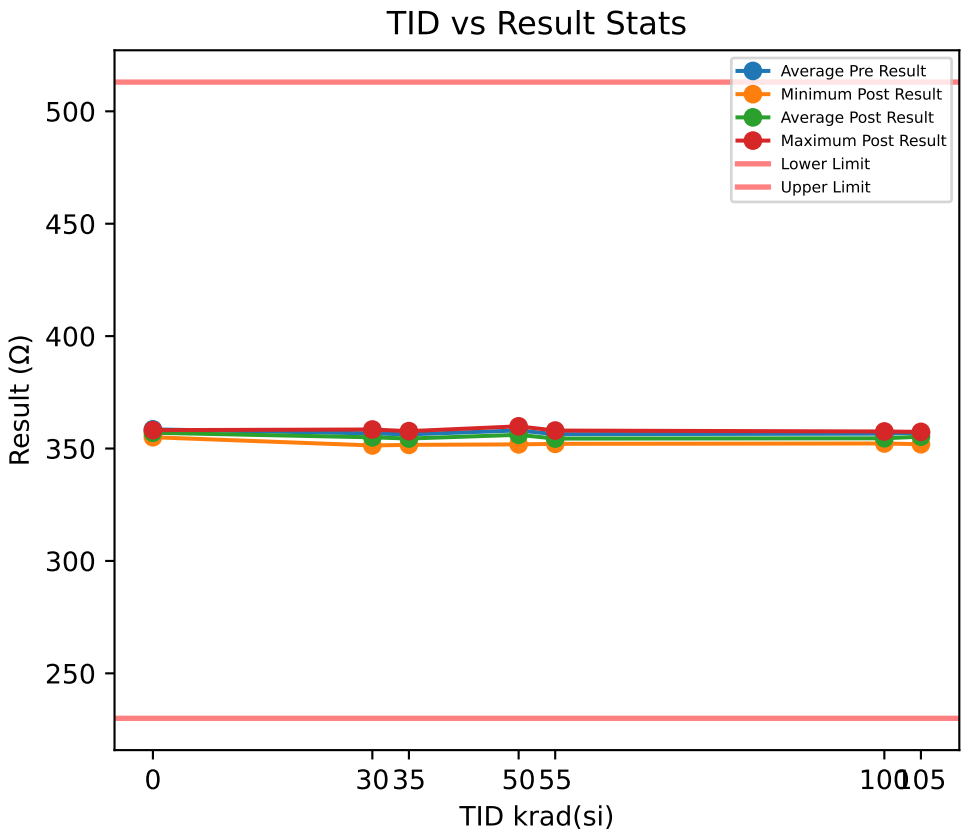
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

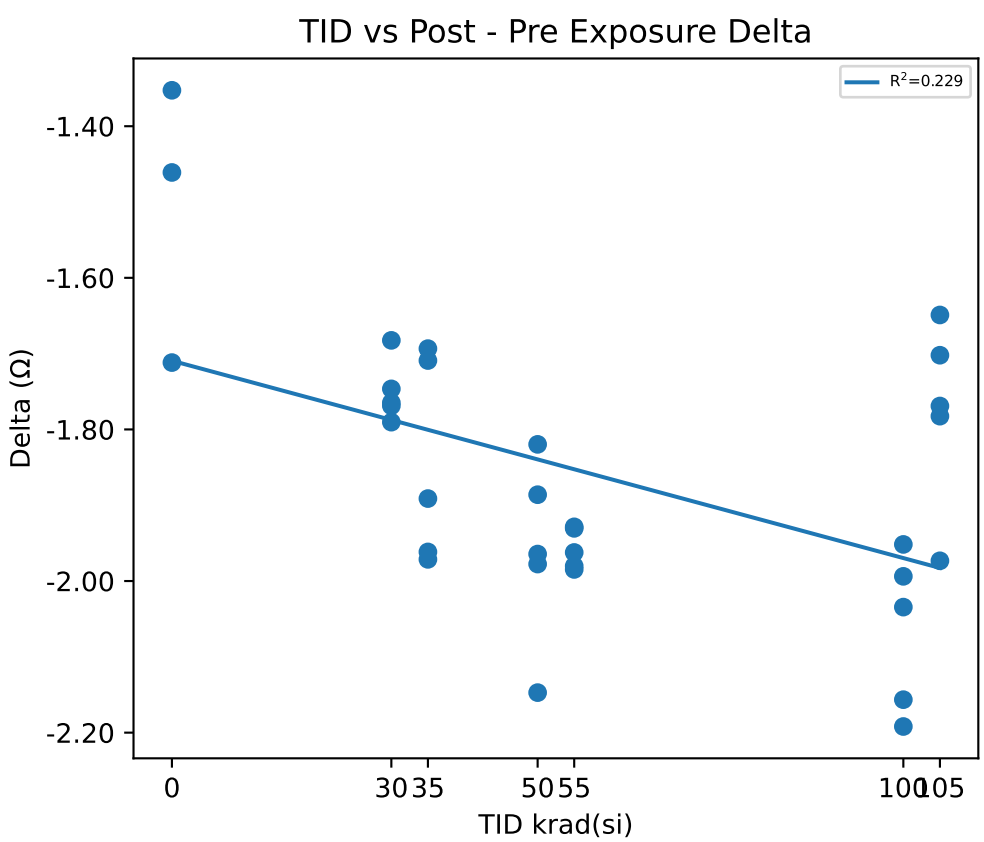
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.2816	2.2843	0.0027
2	0	CU2	2.1097	2.1131	0.0034
3	0	CU3	2.2242	2.2269	0.0027
11	30	Unbiased-30krad	2.3173	2.323	0.0057
12	30	Unbiased-30krad	2.2668	2.2684	0.0016
13	30	Unbiased-30krad	2.3353	2.3436	0.0083
14	30	Unbiased-30krad	2.2631	2.2617	-0.0014
15	30	Unbiased-30krad	2.1996	2.2049	0.0053
16	35	Biased-30krad	2.2645	2.2771	0.0126
17	35	Biased-30krad	2.1975	2.2072	0.0097
18	35	Biased-30krad	2.2607	2.2678	0.0071
19	35	Biased-30krad	2.3945	2.4053	0.0108
20	35	Biased-30krad	2.2087	2.2185	0.0098
30	50	Unbiased-50krad	2.2137	2.2159	0.0022
31	50	Unbiased-50krad	2.3191	2.3253	0.0062
32	50	Unbiased-50krad	2.2572	2.2679	0.0107
33	50	Unbiased-50krad	2.2091	2.2085	-0.0006
34	50	Unbiased-50krad	2.2834	2.2995	0.0161
40	55	Biased-50krad	2.29	2.297	0.007
41	55	Biased-50krad	2.3585	2.3725	0.014
42	55	Biased-50krad	2.2789	2.2968	0.0179
43	55	Biased-50krad	2.265	2.2826	0.0176
44	55	Biased-50krad	2.1635	2.1842	0.0207
45	100	Unbiased-100krad	2.2707	2.2734	0.0027
46	100	Unbiased-100krad	2.109	2.1239	0.0149
47	100	Unbiased-100krad	2.3047	2.3161	0.0114
48	100	Unbiased-100krad	2.4439	2.4574	0.0135
49	100	Unbiased-100krad	2.1567	2.1669	0.0102
50	105	Biased-100krad	2.2179	2.2432	0.0253
51	105	Biased-100krad	2.1868	2.2125	0.0257
52	105	Biased-100krad	2.2955	2.3118	0.0163
53	105	Biased-100krad	2.2514	2.2759	0.0245
54	105	Biased-100krad	2.2483	2.2634	0.0151

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1097	2.2052	2.2816	0.087516	2.1131	2.2081	2.2843	0.087135	0.0027	0.0029333	0.0034	0.00040415
30	2.1996	2.2764	2.3353	0.053173	2.2049	2.2803	2.3436	0.054779	-0.0014	0.0039	0.0083	0.0038059
35	2.1975	2.2652	2.3945	0.078286	2.2072	2.2752	2.4053	0.078777	0.0071	0.01	0.0126	0.0019962
50	2.2091	2.2565	2.3191	0.046694	2.2085	2.2634	2.3253	0.051052	-0.0006	0.00692	0.0161	0.0066691
55	2.1635	2.2712	2.3585	0.070128	2.1842	2.2866	2.3725	0.067255	0.007	0.01544	0.0207	0.0052842
100	2.109	2.257	2.4439	0.13168	2.1239	2.2675	2.4574	0.13153	0.0027	0.01054	0.0149	0.0047458
105	2.1868	2.24	2.2955	0.040613	2.2125	2.2614	2.3118	0.037003	0.0151	0.02138	0.0257	0.0052203

Device Test: 40.5 _SoftStart|Resistance/SS1/3/3///90.9/634//0///@R_SS_DISCHARGE





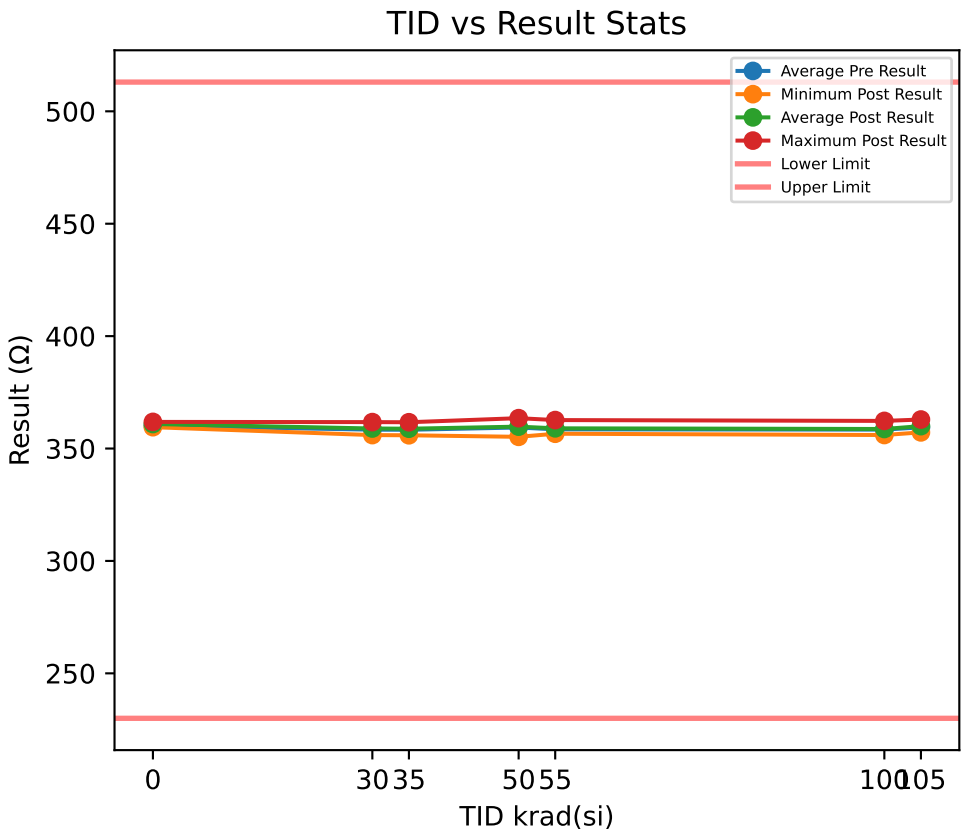
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

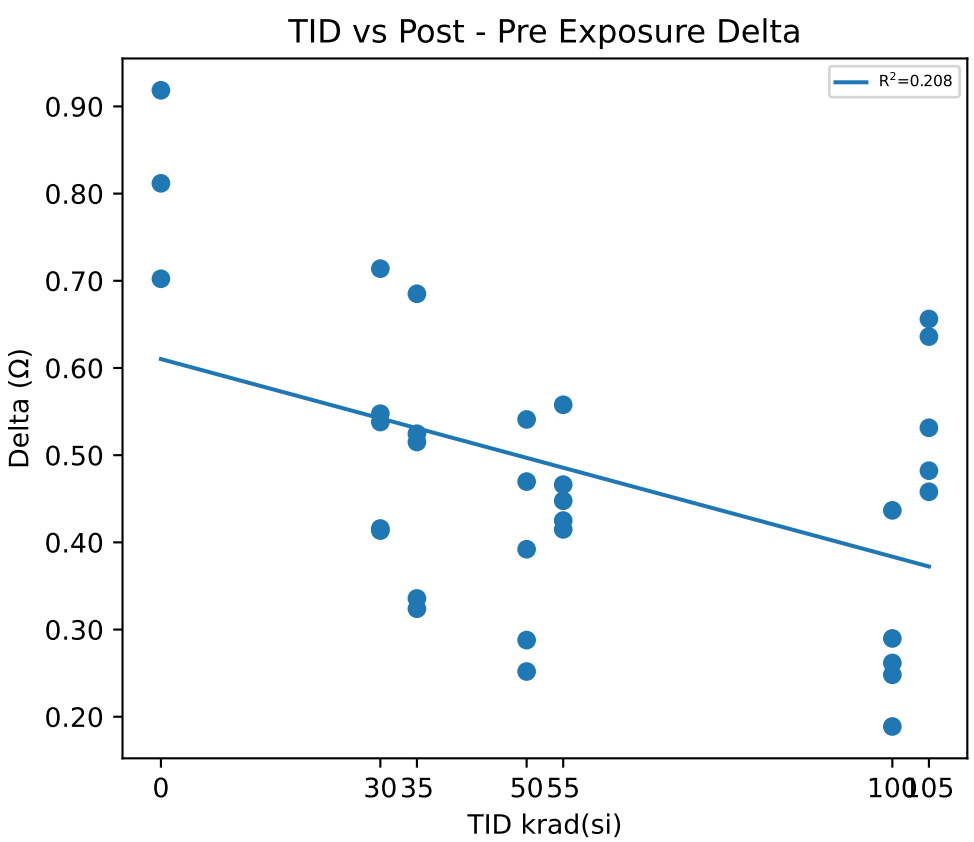
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	359.54	358.18	-1.3526
2	0	CU2	356.49	355.03	-1.461
3	0	CU3	359.56	357.85	-1.7118
11	30	Unbiased-30krad	354.46	352.71	-1.7465
12	30	Unbiased-30krad	358.38	356.7	-1.6825
13	30	Unbiased-30krad	353.13	351.37	-1.7647
14	30	Unbiased-30krad	357.43	355.64	-1.7904
15	30	Unbiased-30krad	360.24	358.47	-1.7688
16	35	Biased-30krad	358.73	357.03	-1.6934
17	35	Biased-30krad	355.86	353.89	-1.9714
18	35	Biased-30krad	359.63	357.73	-1.8912
19	35	Biased-30krad	353.66	351.95	-1.7091
20	35	Biased-30krad	353.59	351.63	-1.9616
30	50	Unbiased-50krad	357.79	355.81	-1.9776
31	50	Unbiased-50krad	353.74	351.85	-1.8861
32	50	Unbiased-50krad	359.99	357.84	-2.1472
33	50	Unbiased-50krad	357.07	355.1	-1.9644
34	50	Unbiased-50krad	361.7	359.88	-1.8197
40	55	Biased-50krad	354.66	352.68	-1.9802
41	55	Biased-50krad	355.35	353.42	-1.9305
42	55	Biased-50krad	359.98	358	-1.9847
43	55	Biased-50krad	357.87	355.91	-1.9623
44	55	Biased-50krad	354.01	352.09	-1.9285
45	100	Unbiased-100krad	354.24	352.25	-1.9938
46	100	Unbiased-100krad	357.91	355.75	-2.1565
47	100	Unbiased-100krad	355.47	353.28	-2.1919
48	100	Unbiased-100krad	355.84	353.89	-1.9517
49	100	Unbiased-100krad	359.63	357.59	-2.0344
50	105	Biased-100krad	358.97	357.27	-1.7021
51	105	Biased-100krad	353.69	351.91	-1.7825
52	105	Biased-100krad	358.36	356.71	-1.649
53	105	Biased-100krad	354.84	353.08	-1.7691
54	105	Biased-100krad	359.38	357.41	-1.9733

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	356.49	358.53	359.56	1.7663	355.03	357.02	358.18	1.7332	-1.7118	-1.5085	-1.3526	0.18424
30	353.13	356.73	360.24	2.9004	351.37	354.98	358.47	2.906	-1.7904	-1.7506	-1.6825	0.041135
35	353.59	356.29	359.63	2.8035	351.63	354.45	357.73	2.8269	-1.9714	-1.8453	-1.6934	0.13524
50	353.74	358.06	361.7	3.0281	351.85	356.1	359.88	3.0173	-2.1472	-1.959	-1.8197	0.123
55	354.01	356.37	359.98	2.4903	352.09	354.42	358	2.4741	-1.9847	-1.9572	-1.9285	0.026683
100	354.24	356.62	359.63	2.1384	352.25	354.55	357.59	2.1248	-2.1919	-2.0657	-1.9517	0.10406
105	353.69	357.05	359.38	2.5981	351.91	355.28	357.41	2.5871	-1.9733	-1.7752	-1.649	0.12309

Device Test: 40.6 _SoftStart|Resistance/SS2/3/3///90.9/634//0///@R_SS_DISCHARGE





Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

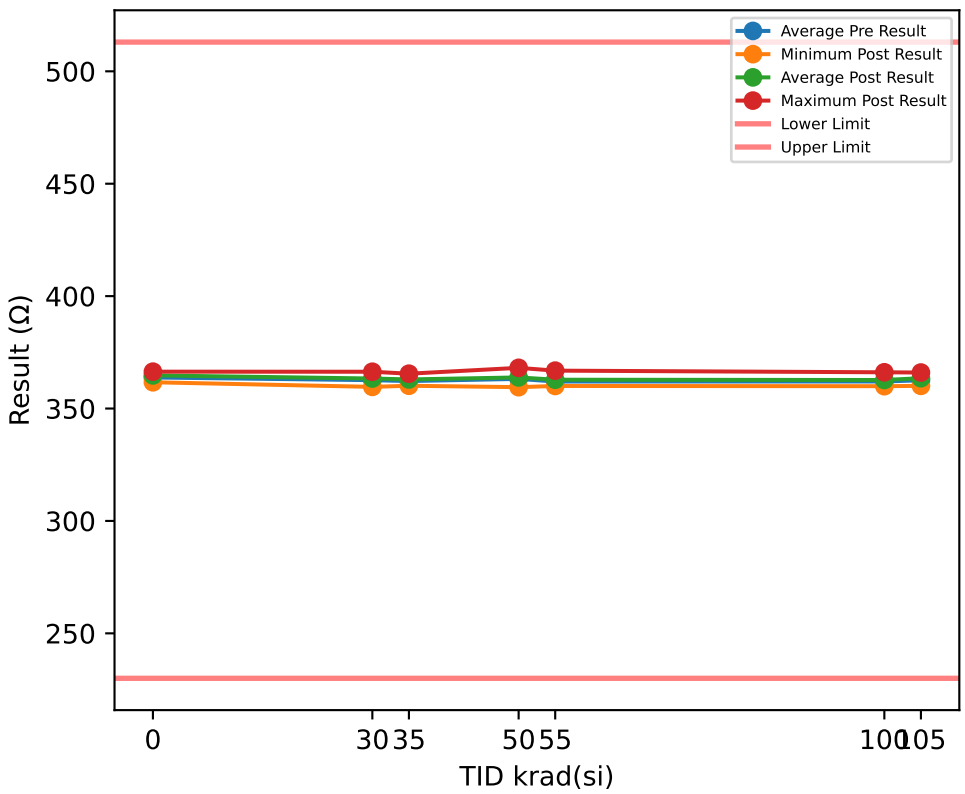
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	361.03	361.85	0.8118
2	0	CU2	358.57	359.49	0.9185
3	0	CU3	360.68	361.38	0.7023
11	30	Unbiased-30krad	356.32	356.73	0.4159
12	30	Unbiased-30krad	360.33	361.05	0.7139
13	30	Unbiased-30krad	355.44	355.98	0.538
14	30	Unbiased-30krad	358.65	359.06	0.4135
15	30	Unbiased-30krad	361.21	361.75	0.5476
16	35	Biased-30krad	361.13	361.64	0.5151
17	35	Biased-30krad	358.05	358.38	0.3239
18	35	Biased-30krad	361.17	361.69	0.5246
19	35	Biased-30krad	355.79	356.47	0.6851
20	35	Biased-30krad	355.56	355.9	0.3357
30	50	Unbiased-50krad	359.29	359.76	0.4697
31	50	Unbiased-50krad	354.95	355.21	0.2519
32	50	Unbiased-50krad	360.63	360.92	0.2879
33	50	Unbiased-50krad	358.92	359.32	0.3921
34	50	Unbiased-50krad	362.96	363.51	0.541
40	55	Biased-50krad	356.82	357.25	0.425
41	55	Biased-50krad	357.82	358.26	0.4477
42	55	Biased-50krad	362.19	362.66	0.4662
43	55	Biased-50krad	359.65	360.21	0.5578
44	55	Biased-50krad	356.16	356.58	0.4149
45	100	Unbiased-100krad	355.83	356.02	0.1888
46	100	Unbiased-100krad	359.64	359.9	0.2617
47	100	Unbiased-100krad	357.27	357.52	0.2481
48	100	Unbiased-100krad	357.32	357.75	0.4367
49	100	Unbiased-100krad	362	362.29	0.2898
50	105	Biased-100krad	361.08	361.54	0.458
51	105	Biased-100krad	356.7	357.19	0.4822
52	105	Biased-100krad	359.81	360.45	0.636
53	105	Biased-100krad	357.1	357.75	0.6562
54	105	Biased-100krad	362.37	362.9	0.5314

Test Statistics (Ω)

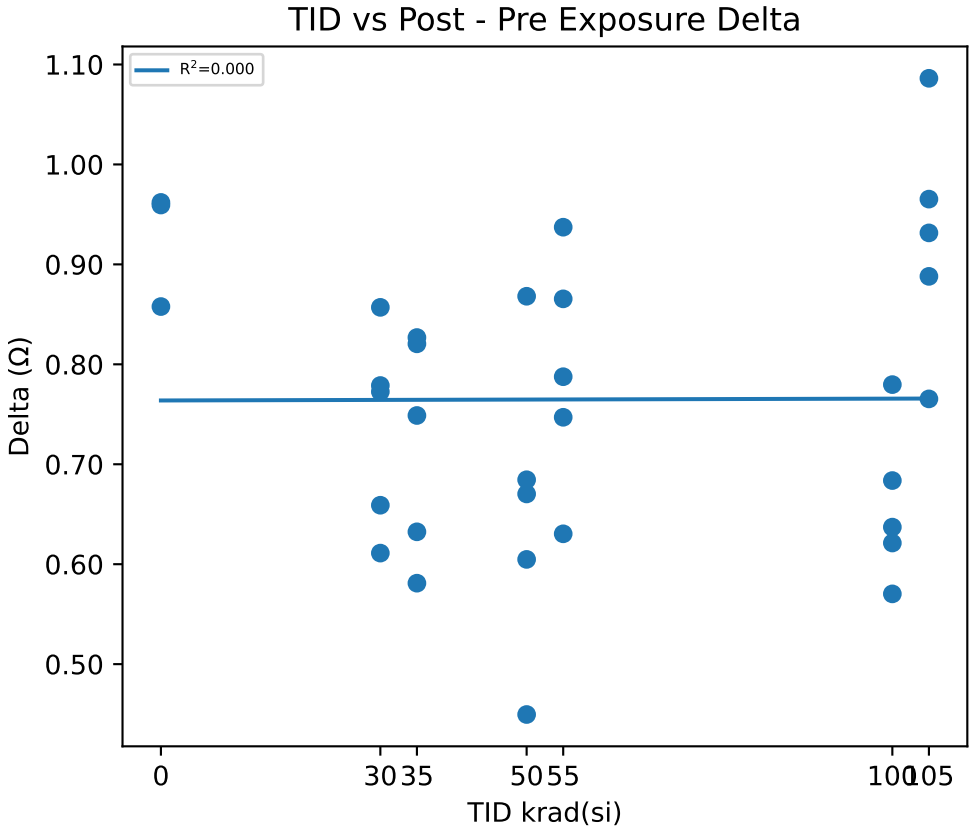
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	358.57	360.1	361.03	1.329	359.49	360.91	361.85	1.2458	0.7023	0.81087	0.9185	0.1081
30	355.44	358.39	361.21	2.4872	355.98	358.92	361.75	2.5487	0.4135	0.52578	0.7139	0.12318
35	355.56	358.34	361.17	2.7421	355.9	358.82	361.69	2.7594	0.3239	0.47688	0.6851	0.15036
50	354.95	359.35	362.96	2.9244	355.21	359.74	363.51	3.0125	0.2519	0.38852	0.541	0.12108
55	356.16	358.53	362.19	2.4345	356.58	358.99	362.66	2.4666	0.4149	0.46232	0.5578	0.05698
100	355.83	358.41	362	2.4264	356.02	358.7	362.29	2.4398	0.1888	0.28502	0.4367	0.092459
105	356.7	359.41	362.37	2.4701	357.19	359.97	362.9	2.4477	0.458	0.55276	0.6562	0.089503

Device Test: 40.7 _SoftStart|Resistance/SS3/3/3///90.9/634//0///@R_SS_DISCHARGE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



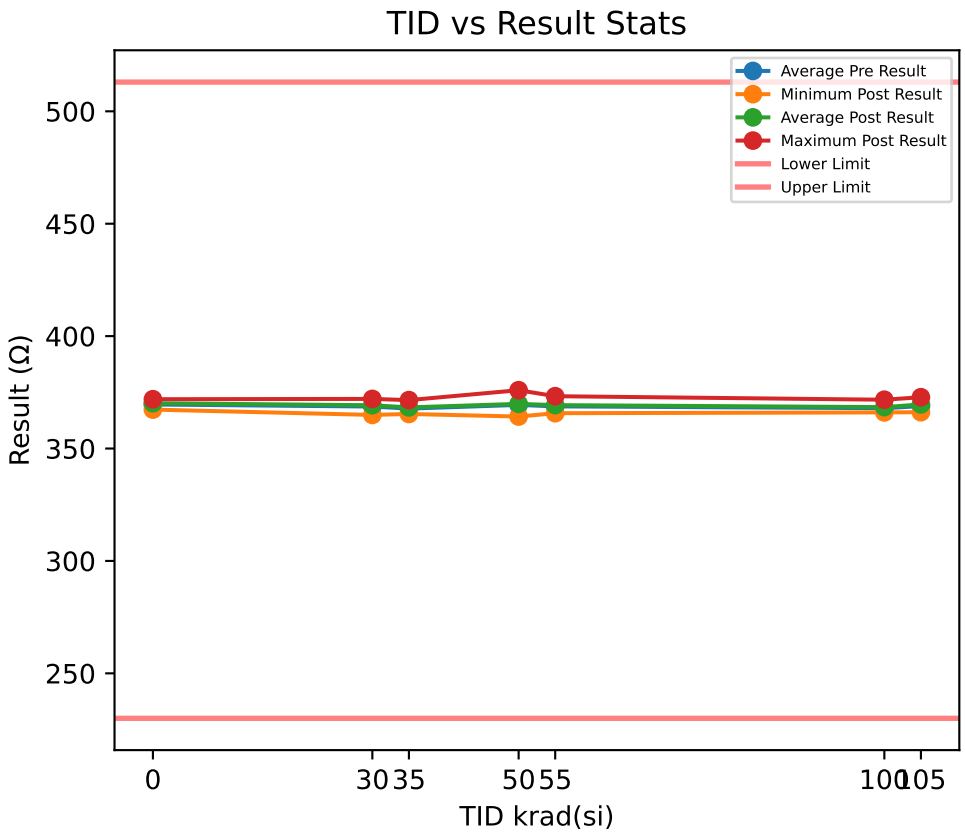
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

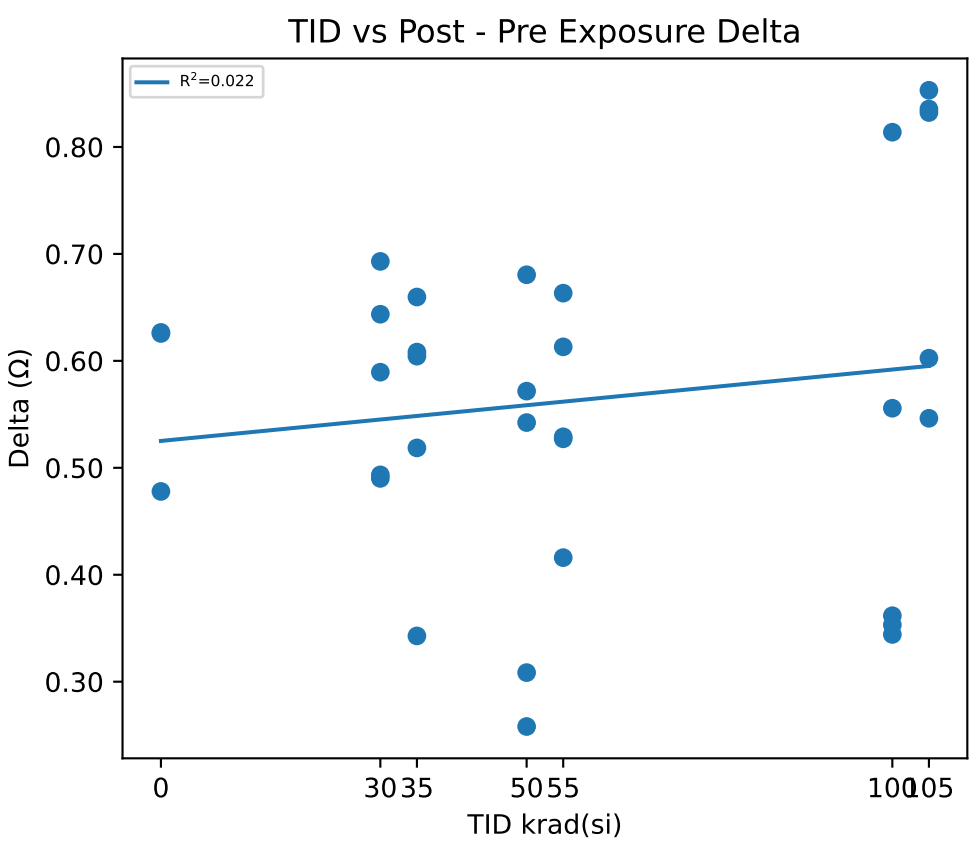
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	365.54	366.4	0.8578
2	0	CU2	360.72	361.68	0.9594
3	0	CU3	365.17	366.14	0.962
11	30	Unbiased-30krad	360.62	361.48	0.857
12	30	Unbiased-30krad	364.01	364.79	0.7788
13	30	Unbiased-30krad	358.98	359.63	0.659
14	30	Unbiased-30krad	363.86	364.47	0.6111
15	30	Unbiased-30krad	365.59	366.37	0.7726
16	35	Biased-30krad	364.65	365.47	0.8268
17	35	Biased-30krad	361.93	362.51	0.581
18	35	Biased-30krad	364.74	365.49	0.7488
19	35	Biased-30krad	360.29	361.11	0.8205
20	35	Biased-30krad	359.5	360.13	0.6324
30	50	Unbiased-50krad	361.86	362.47	0.6048
31	50	Unbiased-50krad	358.83	359.5	0.6703
32	50	Unbiased-50krad	364.85	365.3	0.4496
33	50	Unbiased-50krad	362.93	363.8	0.8681
34	50	Unbiased-50krad	367.42	368.1	0.6845
40	55	Biased-50krad	359.83	360.47	0.6304
41	55	Biased-50krad	361.59	362.38	0.7876
42	55	Biased-50krad	365.92	366.85	0.9372
43	55	Biased-50krad	363.47	364.34	0.8655
44	55	Biased-50krad	359.29	360.04	0.747
45	100	Unbiased-100krad	359.3	359.94	0.6371
46	100	Unbiased-100krad	364.21	364.83	0.6212
47	100	Unbiased-100krad	360.3	360.87	0.5703
48	100	Unbiased-100krad	360.92	361.7	0.7797
49	100	Unbiased-100krad	365.44	366.12	0.6837
50	105	Biased-100krad	364.89	365.77	0.888
51	105	Biased-100krad	359.33	360.09	0.7654
52	105	Biased-100krad	362.87	363.96	1.0862
53	105	Biased-100krad	360.67	361.63	0.9653
54	105	Biased-100krad	365.08	366.01	0.9315

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	360.72	363.81	365.54	2.6823	361.68	364.74	366.4	2.6507	0.8578	0.9264	0.962	0.059424
30	358.98	362.61	365.59	2.7206	359.63	363.35	366.37	2.7272	0.6111	0.7357	0.857	0.099173
35	359.5	362.22	364.74	2.4227	360.13	362.94	365.49	2.4678	0.581	0.7219	0.8268	0.11103
50	358.83	363.18	367.42	3.2192	359.5	363.83	368.1	3.2017	0.4496	0.65546	0.8681	0.15102
55	359.29	362.02	365.92	2.7243	360.04	362.82	366.85	2.8303	0.6304	0.79354	0.9372	0.11687
100	359.3	362.03	365.44	2.6479	359.94	362.69	366.12	2.6566	0.5703	0.6584	0.7797	0.078982
105	359.33	362.57	365.08	2.5442	360.09	363.49	366.01	2.5878	0.7654	0.92728	1.0862	0.11669

Device Test: 40.8 _SoftStart|Resistance/SS4/3/3///90.9/634//0///@R_SS_DISCHARGE





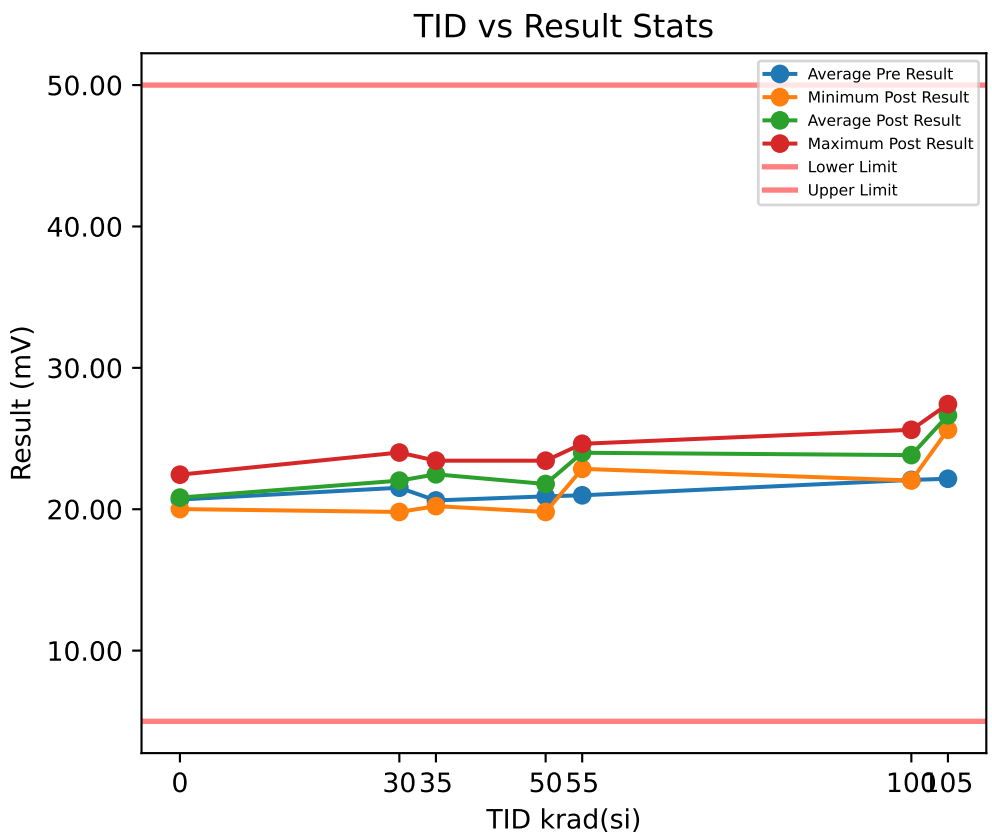
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

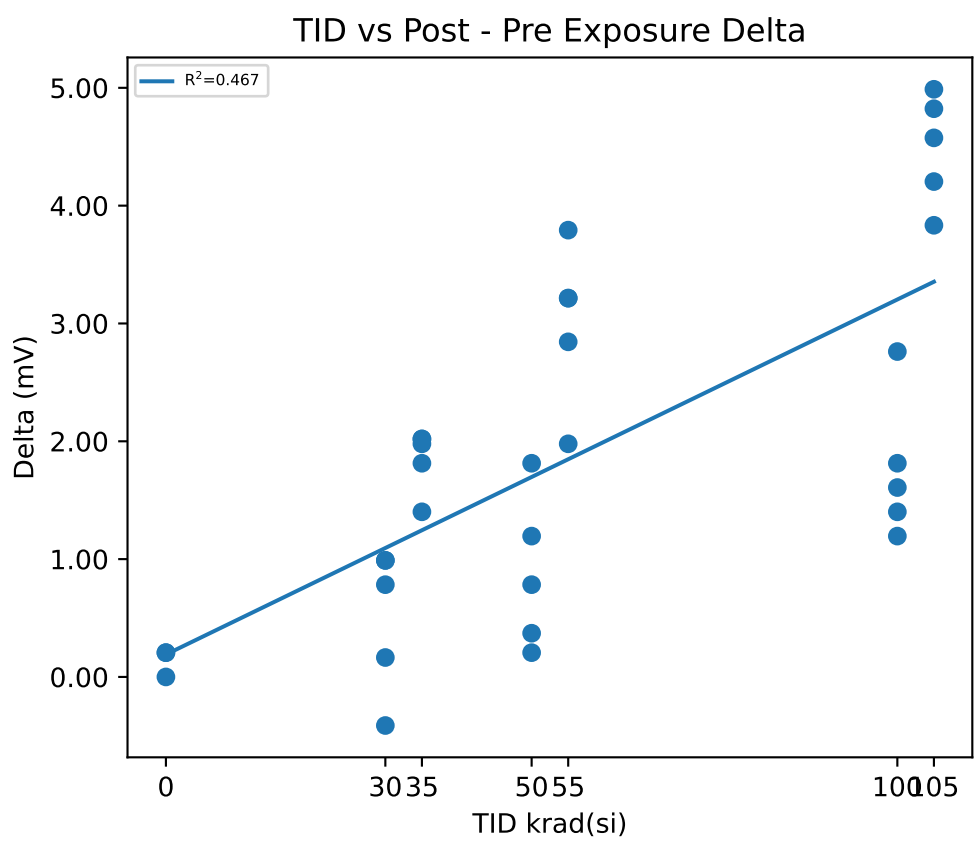
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	370.74	371.22	0.4779
2	0	CU2	366.69	367.32	0.6266
3	0	CU3	371.31	371.94	0.6256
11	30	Unbiased-30krad	367.27	367.86	0.5894
12	30	Unbiased-30krad	370	370.69	0.693
13	30	Unbiased-30krad	364.31	364.96	0.6436
14	30	Unbiased-30krad	370.21	370.7	0.4901
15	30	Unbiased-30krad	371.58	372.07	0.4934
16	35	Biased-30krad	370.94	371.54	0.6044
17	35	Biased-30krad	367.43	367.77	0.3428
18	35	Biased-30krad	370.79	371.4	0.6082
19	35	Biased-30krad	364.71	365.37	0.6597
20	35	Biased-30krad	364.88	365.4	0.5186
30	50	Unbiased-50krad	368.37	368.68	0.3085
31	50	Unbiased-50krad	363.69	364.23	0.5423
32	50	Unbiased-50krad	370.34	370.6	0.2581
33	50	Unbiased-50krad	369.25	369.93	0.6805
34	50	Unbiased-50krad	375.37	375.95	0.5717
40	55	Biased-50krad	366.82	367.24	0.416
41	55	Biased-50krad	368.24	368.85	0.6131
42	55	Biased-50krad	372.62	373.28	0.6633
43	55	Biased-50krad	370.9	371.43	0.529
44	55	Biased-50krad	365.19	365.71	0.5271
45	100	Unbiased-100krad	365.52	366.07	0.5557
46	100	Unbiased-100krad	369.18	369.53	0.3531
47	100	Unbiased-100krad	365.86	366.22	0.3617
48	100	Unbiased-100krad	367.78	368.59	0.8138
49	100	Unbiased-100krad	371.37	371.71	0.3442
50	105	Biased-100krad	370.66	371.27	0.6025
51	105	Biased-100krad	365.62	366.17	0.5463
52	105	Biased-100krad	369.38	370.23	0.853
53	105	Biased-100krad	366.74	367.58	0.8355
54	105	Biased-100krad	371.99	372.82	0.8322

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	366.69	369.58	371.31	2.5186	367.32	370.16	371.94	2.4852	0.4779	0.5767	0.6266	0.085565
30	364.31	368.68	371.58	2.8967	364.96	369.26	372.07	2.8519	0.4901	0.5819	0.693	0.090091
35	364.71	367.75	370.94	3.0408	365.37	368.29	371.54	3.0576	0.3428	0.54674	0.6597	0.12475
50	363.69	369.4	375.37	4.192	364.23	369.88	375.95	4.2036	0.2581	0.47222	0.6805	0.18086
55	365.19	368.75	372.62	3.0112	365.71	369.3	373.28	3.0703	0.416	0.5497	0.6633	0.094524
100	365.52	367.94	371.37	2.4238	366.07	368.43	371.71	2.3683	0.3442	0.4857	0.8138	0.20343
105	365.62	368.88	371.99	2.6594	366.17	369.61	372.82	2.7123	0.5463	0.7339	0.853	0.14716

Device Test: 40.9 _SoftStart|MaxStartupVoltage/SS1/3/3///90.9/634//0///@V_SS_START





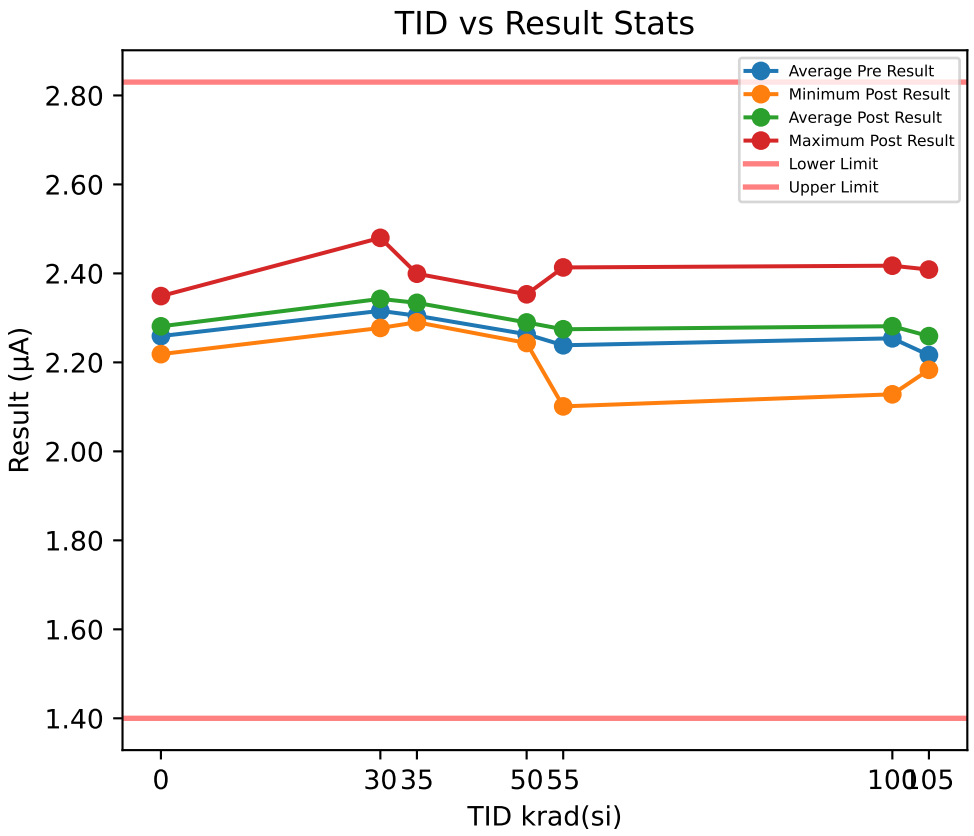
Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

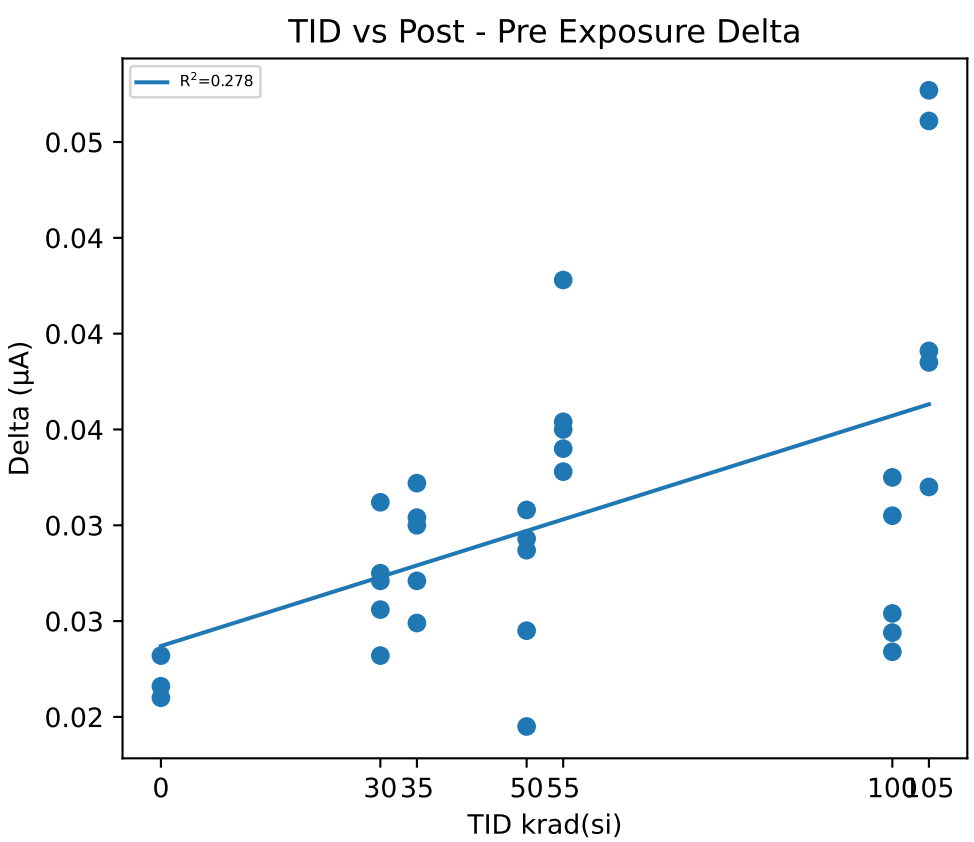
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	20.012	20.012	0
2	0	CU2	22.238	22.444	0.2061
3	0	CU3	19.806	20.012	0.2061
11	30	Unbiased-30krad	22.65	22.238	-0.4122
12	30	Unbiased-30krad	21.249	22.238	0.9892
13	30	Unbiased-30krad	19.641	19.806	0.1649
14	30	Unbiased-30krad	21.043	21.826	0.7831
15	30	Unbiased-30krad	23.021	24.011	0.9893
16	35	Biased-30krad	18.198	20.218	2.0198
17	35	Biased-30krad	21.043	23.021	1.9785
18	35	Biased-30krad	22.032	23.433	1.4015
19	35	Biased-30krad	20.424	22.444	2.0197
20	35	Biased-30krad	21.414	23.227	1.8137
30	50	Unbiased-50krad	22.65	23.433	0.7832
31	50	Unbiased-50krad	19.806	21.62	1.8136
32	50	Unbiased-50krad	21.043	22.238	1.1953
33	50	Unbiased-50krad	19.435	19.806	0.371
34	50	Unbiased-50krad	21.62	21.826	0.2061
40	55	Biased-50krad	20.012	22.856	2.8441
41	55	Biased-50krad	20.631	24.423	3.7922
42	55	Biased-50krad	21.414	24.629	3.2152
43	55	Biased-50krad	20.424	23.64	3.2151
44	55	Biased-50krad	22.444	24.423	1.9786
45	100	Unbiased-100krad	22.856	25.618	2.7617
46	100	Unbiased-100krad	20.631	22.032	1.4014
47	100	Unbiased-100krad	23.433	24.629	1.1954
48	100	Unbiased-100krad	22.032	23.846	1.8137
49	100	Unbiased-100krad	21.414	23.021	1.6076
50	105	Biased-100krad	23.021	26.855	3.8334
51	105	Biased-100krad	22.238	26.442	4.2044
52	105	Biased-100krad	21.043	25.618	4.5753
53	105	Biased-100krad	22.444	27.432	4.9876
54	105	Biased-100krad	22.032	26.855	4.8227

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.806	20.685	22.238	1.3485	20.012	20.823	22.444	1.4041	0	0.1374	0.2061	0.11899
30	19.641	21.521	23.021	1.3567	19.806	22.024	24.011	1.4997	-0.4122	0.50286	0.9893	0.61303
35	18.198	20.622	22.032	1.4751	20.218	22.469	23.433	1.3111	1.4015	1.8466	2.0198	0.26294
50	19.435	20.911	22.65	1.3175	19.806	21.785	23.433	1.3103	0.2061	0.87384	1.8136	0.65066
55	20.012	20.985	22.444	0.96163	22.856	23.994	24.629	0.74003	1.9786	3.009	3.7922	0.66845
100	20.631	22.073	23.433	1.116	22.032	23.829	25.618	1.3895	1.1954	1.756	2.7617	0.60762
105	21.043	22.156	23.021	0.72338	25.618	26.64	27.432	0.67127	3.8334	4.4847	4.9876	0.46854

Device Test: 41.1 _SoftStart|ChargeCurrent/SS1/7/7///90.9/634//0///@I_SS





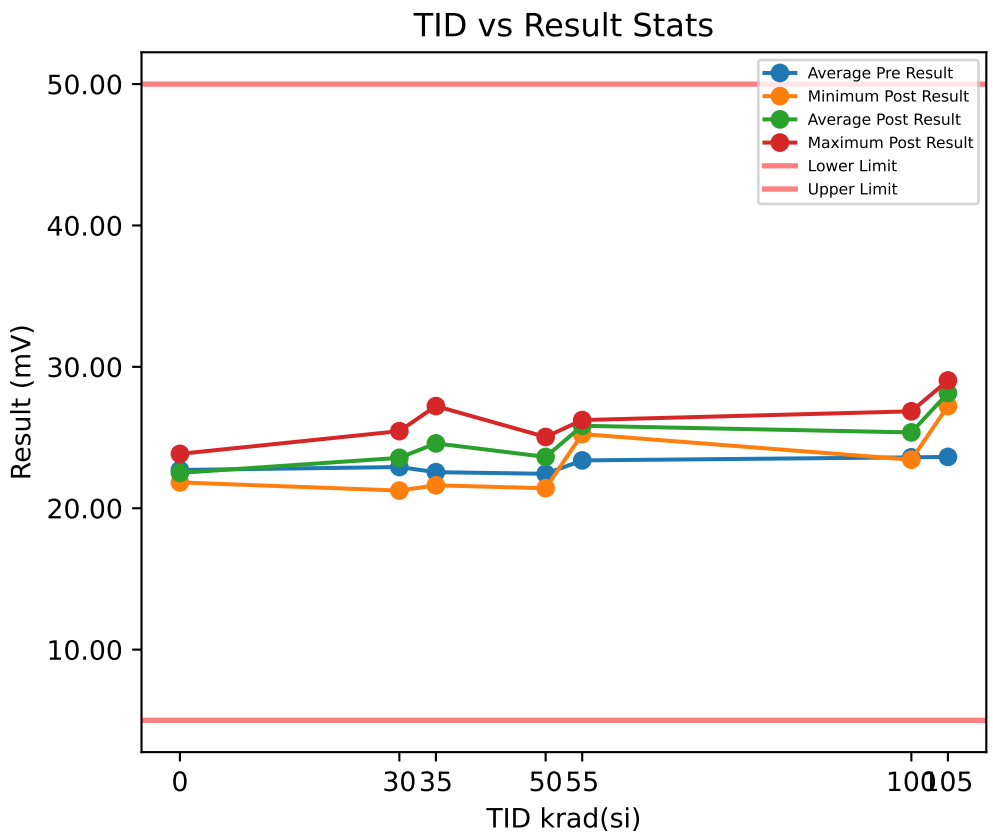
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

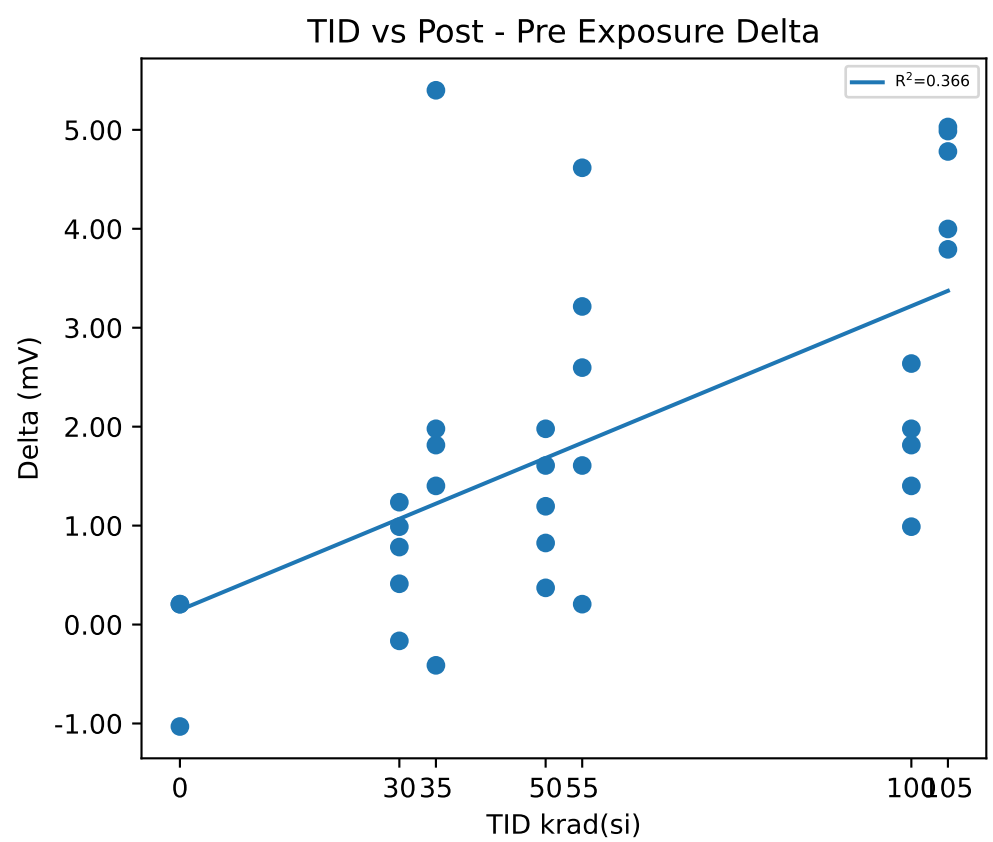
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3258	2.349	0.0232
2	0	CU2	2.2546	2.2756	0.021
3	0	CU3	2.1969	2.2185	0.0216
11	30	Unbiased-30krad	2.2542	2.2774	0.0232
12	30	Unbiased-30krad	2.3261	2.3517	0.0256
13	30	Unbiased-30krad	2.4487	2.4799	0.0312
14	30	Unbiased-30krad	2.2877	2.3148	0.0271
15	30	Unbiased-30krad	2.2623	2.2898	0.0275
16	35	Biased-30krad	2.2602	2.2902	0.03
17	35	Biased-30krad	2.3156	2.346	0.0304
18	35	Biased-30krad	2.2957	2.3206	0.0249
19	35	Biased-30krad	2.3671	2.3993	0.0322
20	35	Biased-30krad	2.2858	2.3129	0.0271
30	50	Unbiased-50krad	2.2542	2.2787	0.0245
31	50	Unbiased-50krad	2.2351	2.2638	0.0287
32	50	Unbiased-50krad	2.2804	2.3097	0.0293
33	50	Unbiased-50krad	2.2241	2.2436	0.0195
34	50	Unbiased-50krad	2.3222	2.353	0.0308
40	55	Biased-50krad	2.2791	2.3119	0.0328
41	55	Biased-50krad	2.2107	2.2447	0.034
42	55	Biased-50krad	2.378	2.4134	0.0354
43	55	Biased-50krad	2.2583	2.3011	0.0428
44	55	Biased-50krad	2.0661	2.1011	0.035
45	100	Unbiased-100krad	2.2462	2.2696	0.0234
46	100	Unbiased-100krad	2.1028	2.1282	0.0254
47	100	Unbiased-100krad	2.277	2.3014	0.0244
48	100	Unbiased-100krad	2.3868	2.4173	0.0305
49	100	Unbiased-100krad	2.2575	2.29	0.0325
50	105	Biased-100krad	2.3575	2.4086	0.0511
51	105	Biased-100krad	2.1674	2.2059	0.0385
52	105	Biased-100krad	2.1466	2.1857	0.0391
53	105	Biased-100krad	2.1306	2.1833	0.0527
54	105	Biased-100krad	2.2794	2.3114	0.032

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1969	2.2591	2.3258	0.064568	2.2185	2.281	2.349	0.065419	0.021	0.021933	0.0232	0.0011372
30	2.2542	2.3158	2.4487	0.079396	2.2774	2.3427	2.4799	0.081771	0.0232	0.02692	0.0312	0.0029269
35	2.2602	2.3049	2.3671	0.040096	2.2902	2.3338	2.3993	0.041687	0.0249	0.02892	0.0322	0.0028978
50	2.2241	2.2632	2.3222	0.039295	2.2436	2.2898	2.353	0.04279	0.0195	0.02656	0.0308	0.0045867
55	2.0661	2.2384	2.378	0.11401	2.1011	2.2744	2.4134	0.11441	0.0328	0.036	0.0428	0.0039319
100	2.1028	2.2541	2.3868	0.10136	2.1282	2.2813	2.4173	0.10314	0.0234	0.02724	0.0325	0.0040153
105	2.1306	2.2163	2.3575	0.098123	2.1833	2.259	2.4086	0.098804	0.032	0.04268	0.0527	0.0088832

Device Test: 41.10 _SoftStart|MaxStartupVoltage/SS2/7/7///90.9/634//0///@V_SS_START





Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

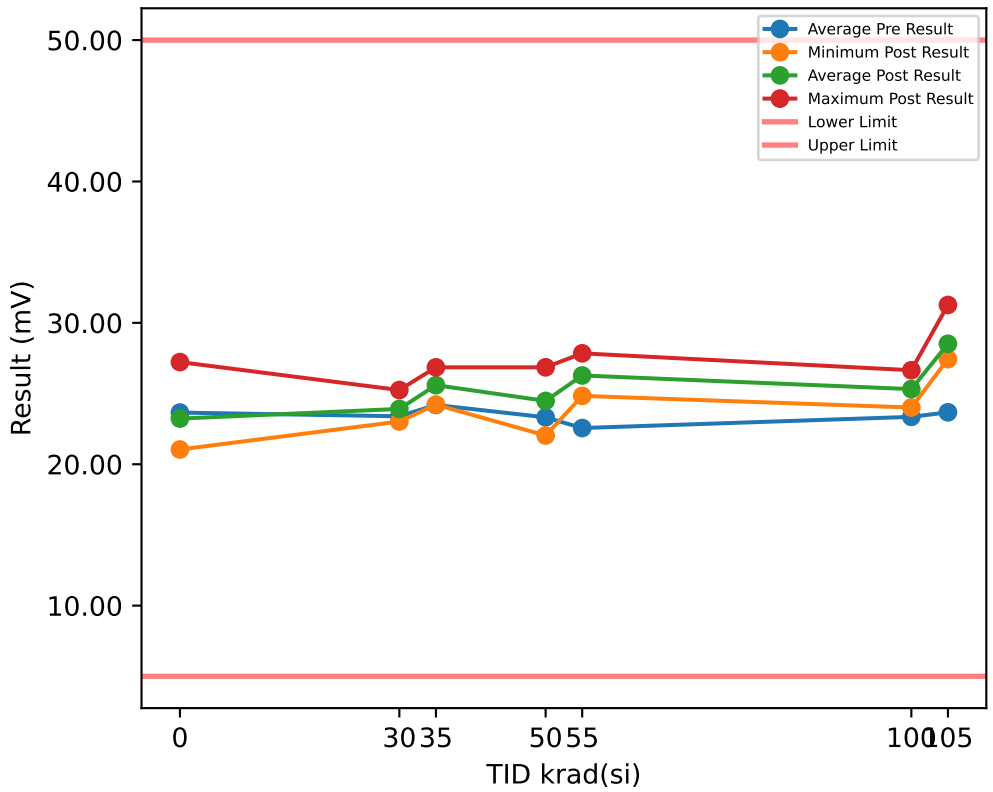
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	22.856	21.826	-1.0305
2	0	CU2	23.64	23.846	0.2061
3	0	CU3	21.62	21.826	0.2061
11	30	Unbiased-30krad	24.011	23.846	-0.1649
12	30	Unbiased-30krad	22.856	23.846	0.9893
13	30	Unbiased-30krad	20.837	21.249	0.4122
14	30	Unbiased-30krad	22.65	23.433	0.7832
15	30	Unbiased-30krad	24.217	25.453	1.2366
16	35	Biased-30krad	22.032	21.62	-0.4122
17	35	Biased-30krad	22.444	24.423	1.9786
18	35	Biased-30krad	23.433	24.835	1.4015
19	35	Biased-30krad	21.826	27.226	5.3998
20	35	Biased-30krad	23.021	24.835	1.8137
30	50	Unbiased-50krad	24.217	25.041	0.8244
31	50	Unbiased-50krad	21.249	23.227	1.9785
32	50	Unbiased-50krad	22.444	23.64	1.1954
33	50	Unbiased-50krad	21.043	21.414	0.3709
34	50	Unbiased-50krad	23.227	24.835	1.6076
40	55	Biased-50krad	21.414	26.03	4.6166
41	55	Biased-50krad	25.824	26.03	0.2061
42	55	Biased-50krad	23.021	26.236	3.2151
43	55	Biased-50krad	22.65	25.247	2.5969
44	55	Biased-50krad	24.011	25.618	1.6075
45	100	Unbiased-100krad	24.217	26.855	2.638
46	100	Unbiased-100krad	22.032	23.433	1.4015
47	100	Unbiased-100krad	25.247	26.236	0.9892
48	100	Unbiased-100krad	23.64	25.453	1.8137
49	100	Unbiased-100krad	22.856	24.835	1.9786
50	105	Biased-100krad	24.629	28.421	3.7922
51	105	Biased-100krad	23.64	27.638	3.9983
52	105	Biased-100krad	22.444	27.226	4.7815
53	105	Biased-100krad	24.011	29.039	5.0288
54	105	Biased-100krad	23.433	28.421	4.9876

Test Statistics (mV)

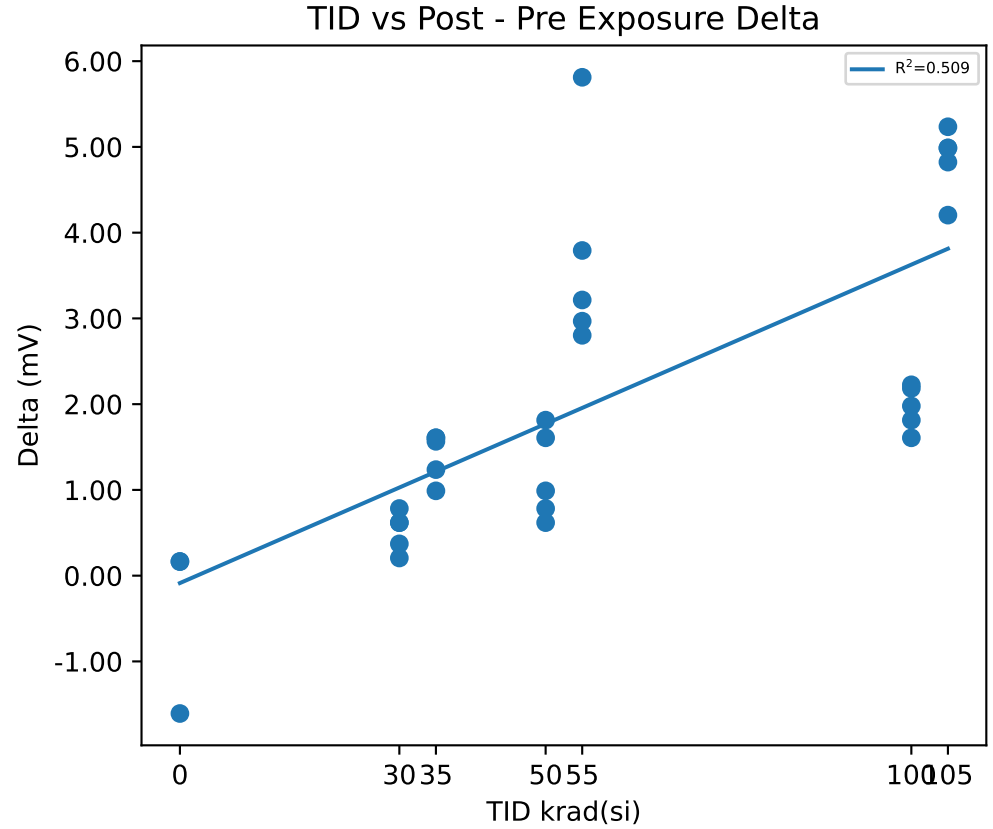
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.62	22.705	23.64	1.0183	21.826	22.499	23.846	1.1661	-1.0305	-0.2061	0.2061	0.71395
30	20.837	22.914	24.217	1.3498	21.249	23.565	25.453	1.5087	-0.1649	0.65128	1.2366	0.54717
35	21.826	22.551	23.433	0.67204	21.62	24.588	27.226	1.9948	-0.4122	2.0363	5.3998	2.1074
50	21.043	22.436	24.217	1.3367	21.414	23.631	25.041	1.4592	0.3709	1.1954	1.9785	0.63257
55	21.414	23.384	25.824	1.6507	25.247	25.832	26.236	0.39684	0.2061	2.4484	4.6166	1.6618
100	22.032	23.598	25.247	1.2356	23.433	25.362	26.855	1.3227	0.9892	1.7642	2.638	0.62131
105	22.444	23.631	24.629	0.80428	27.226	28.149	29.039	0.71669	3.7922	4.5177	5.0288	0.58046

Device Test: 41.11 _SoftStart|MaxStartupVoltage/SS3/7/7///90.9/634//0///@V_SS_START

TID vs Result Stats



TID vs Post - Pre Exposure Delta



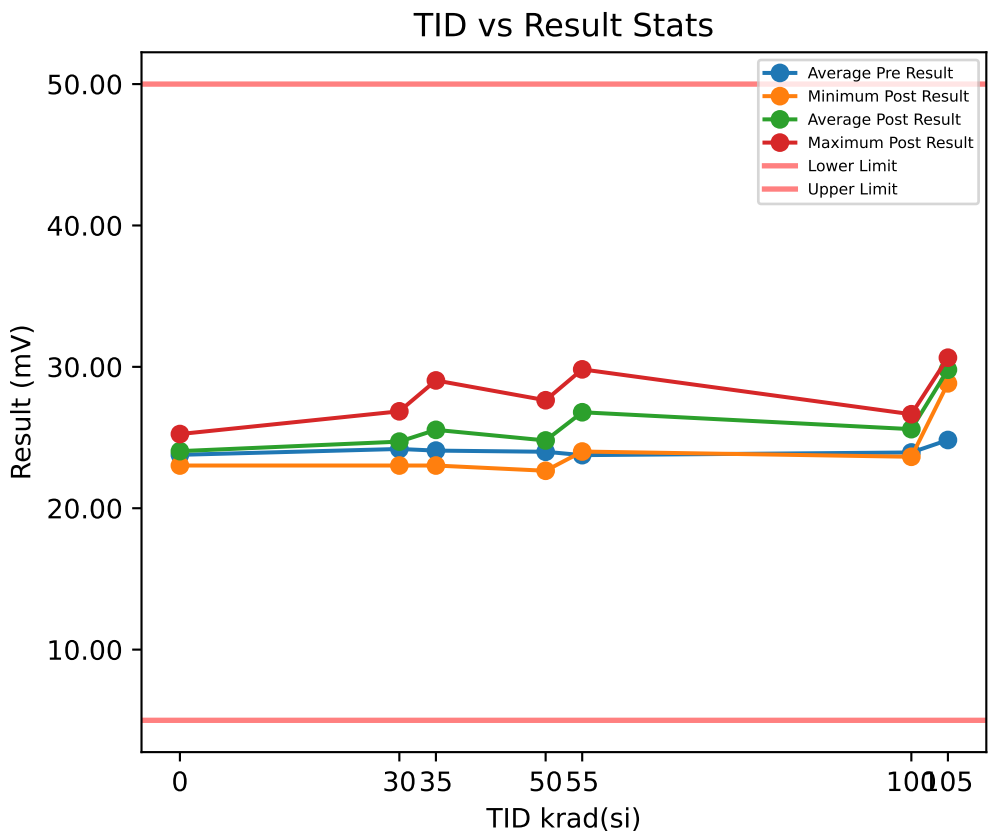
Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

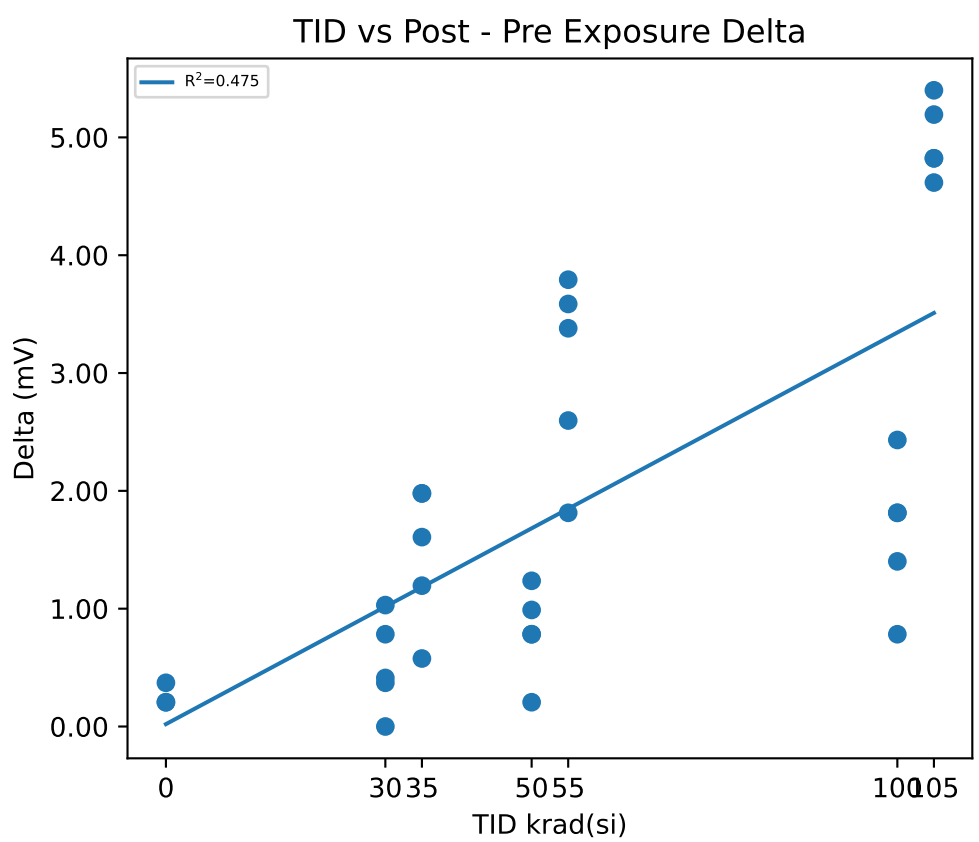
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	22.65	21.043	-1.6075
2	0	CU2	27.061	27.226	0.1649
3	0	CU3	21.249	21.414	0.1648
11	30	Unbiased-30krad	24.011	24.629	0.6183
12	30	Unbiased-30krad	23.433	23.64	0.2061
13	30	Unbiased-30krad	24.629	25.247	0.6183
14	30	Unbiased-30krad	22.238	23.021	0.7832
15	30	Unbiased-30krad	22.65	23.021	0.371
16	35	Biased-30krad	22.65	24.217	1.5664
17	35	Biased-30krad	24.011	25.247	1.2366
18	35	Biased-30krad	24.835	25.824	0.9892
19	35	Biased-30krad	25.247	26.855	1.6075
20	35	Biased-30krad	24.217	25.824	1.6075
30	50	Unbiased-50krad	23.846	25.453	1.6076
31	50	Unbiased-50krad	21.414	22.032	0.6183
32	50	Unbiased-50krad	25.041	26.855	1.8136
33	50	Unbiased-50krad	22.65	23.64	0.9893
34	50	Unbiased-50krad	23.64	24.423	0.7832
40	55	Biased-50krad	25.041	27.844	2.8029
41	55	Biased-50krad	22.856	25.824	2.9678
42	55	Biased-50krad	20.837	26.648	5.8119
43	55	Biased-50krad	21.043	24.835	3.7922
44	55	Biased-50krad	23.021	26.236	3.2151
45	100	Unbiased-100krad	23.433	25.247	1.8137
46	100	Unbiased-100krad	24.423	26.648	2.2258
47	100	Unbiased-100krad	23.433	25.041	1.6076
48	100	Unbiased-100krad	23.64	25.618	1.9785
49	100	Unbiased-100krad	21.826	24.011	2.1847
50	105	Biased-100krad	23.021	27.844	4.8227
51	105	Biased-100krad	26.03	31.265	5.2349
52	105	Biased-100krad	22.444	27.432	4.9876
53	105	Biased-100krad	24.423	28.627	4.2044
54	105	Biased-100krad	22.444	27.432	4.9876

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.249	23.653	27.061	3.033	21.043	23.227	27.226	3.4676	-1.6075	-0.42593	0.1649	1.0233
30	22.238	23.392	24.629	0.97416	23.021	23.912	25.247	0.99469	0.2061	0.51938	0.7832	0.22876
35	22.65	24.192	25.247	0.99213	24.217	25.593	26.855	0.9634	0.9892	1.4014	1.6075	0.27805
50	21.414	23.318	25.041	1.3623	22.032	24.48	26.855	1.8227	0.6183	1.1624	1.8136	0.52251
55	20.837	22.56	25.041	1.7123	24.835	26.278	27.844	1.1045	2.8029	3.718	5.8119	1.2291
100	21.826	23.351	24.423	0.94493	24.011	25.313	26.648	0.95543	1.6076	1.9621	2.2258	0.25838
105	22.444	23.672	26.03	1.5463	27.432	28.52	31.265	1.6104	4.2044	4.8474	5.2349	0.38844

Device Test: 41.12 _SoftStart|MaxStartupVoltage/SS4/7/7///90.9/634//0///@V_SS_START





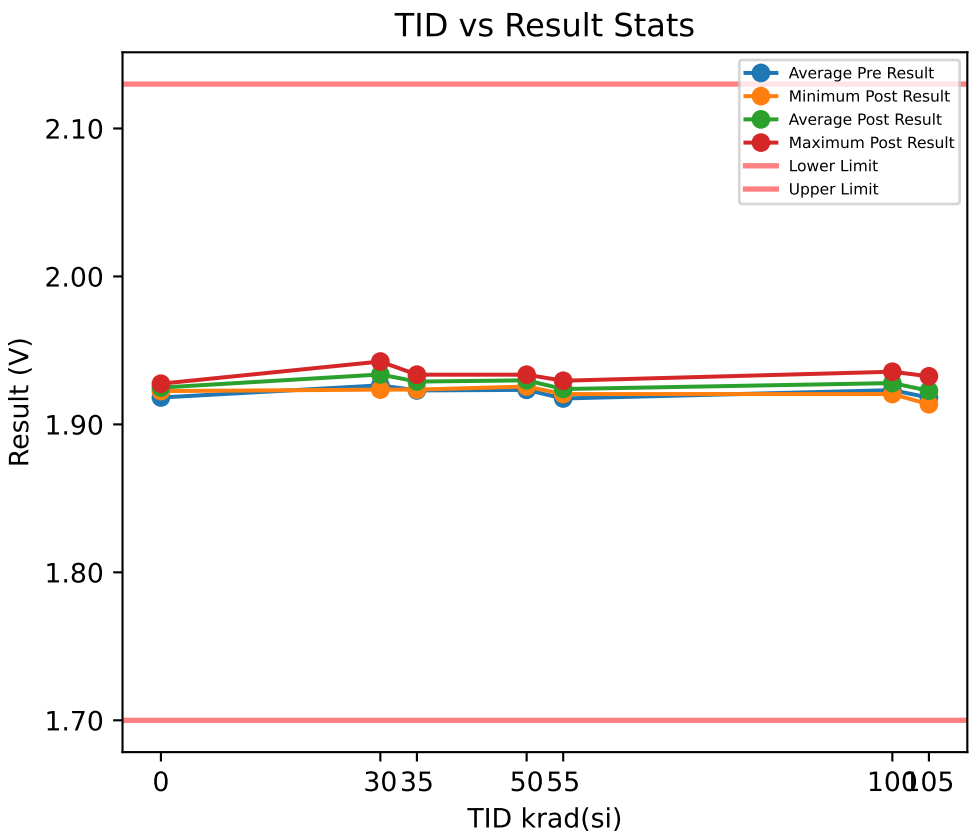
Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

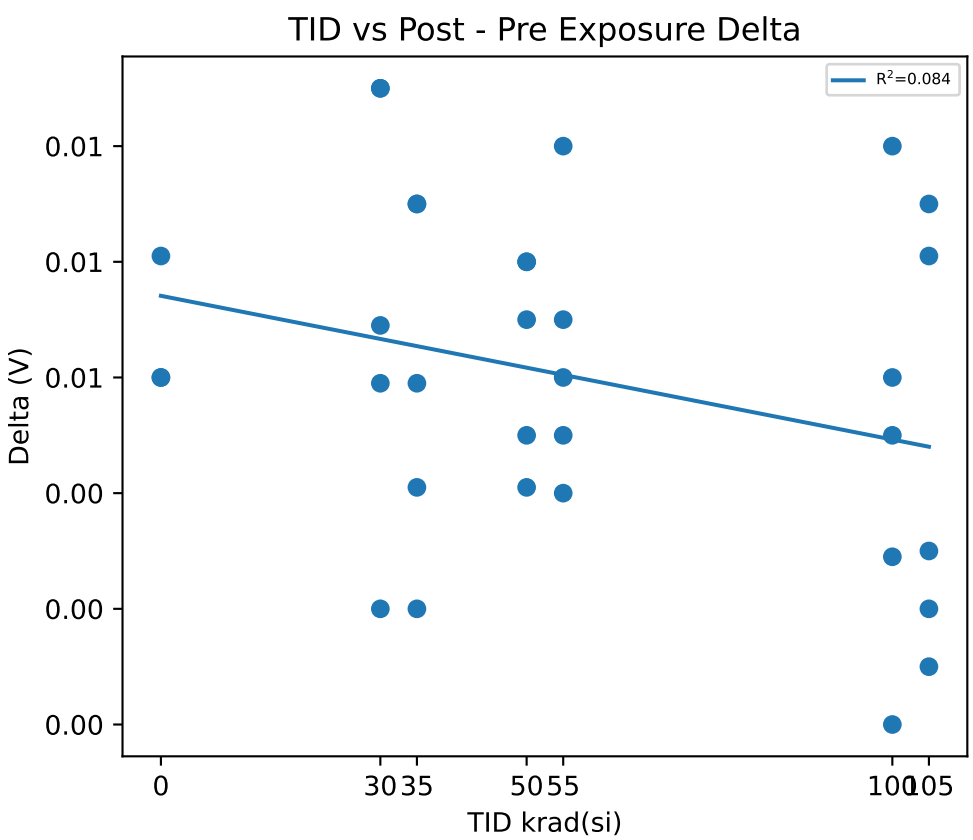
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	25.041	25.247	0.2061
2	0	CU2	23.64	23.846	0.2061
3	0	CU3	22.65	23.021	0.371
11	30	Unbiased-30krad	23.433	24.217	0.7832
12	30	Unbiased-30krad	23.64	24.011	0.371
13	30	Unbiased-30krad	25.041	25.453	0.4122
14	30	Unbiased-30krad	25.824	26.855	1.0305
15	30	Unbiased-30krad	23.021	23.021	0
16	35	Biased-30krad	24.011	25.618	1.6075
17	35	Biased-30krad	27.061	29.039	1.9786
18	35	Biased-30krad	22.444	23.021	0.5771
19	35	Biased-30krad	23.227	24.423	1.1954
20	35	Biased-30krad	23.64	25.618	1.9785
30	50	Unbiased-50krad	23.227	24.217	0.9893
31	50	Unbiased-50krad	21.414	22.65	1.2366
32	50	Unbiased-50krad	24.629	24.835	0.2061
33	50	Unbiased-50krad	26.855	27.638	0.7832
34	50	Unbiased-50krad	23.846	24.629	0.7832
40	55	Biased-50krad	23.227	25.041	1.8137
41	55	Biased-50krad	21.414	24.011	2.5969
42	55	Biased-50krad	26.236	29.823	3.5862
43	55	Biased-50krad	25.041	28.421	3.38
44	55	Biased-50krad	22.856	26.648	3.7922
45	100	Unbiased-100krad	25.041	25.824	0.7831
46	100	Unbiased-100krad	22.238	23.64	1.4015
47	100	Unbiased-100krad	24.217	26.648	2.4319
48	100	Unbiased-100krad	24.217	26.03	1.8136
49	100	Unbiased-100krad	24.011	25.824	1.8136
50	105	Biased-100krad	24.011	28.833	4.8227
51	105	Biased-100krad	26.03	30.647	4.6167
52	105	Biased-100krad	24.423	29.823	5.3998
53	105	Biased-100krad	25.453	30.647	5.1937
54	105	Biased-100krad	24.217	29.039	4.8227

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.65	23.777	25.041	1.2013	23.021	24.038	25.247	1.1253	0.2061	0.26107	0.371	0.095205
30	23.021	24.192	25.824	1.187	23.021	24.711	26.855	1.4779	0	0.51938	1.0305	0.39815
35	22.444	24.076	27.061	1.7668	23.021	25.544	29.039	2.2277	0.5771	1.4674	1.9786	0.59346
50	21.414	23.994	26.855	1.9909	22.65	24.794	27.638	1.8059	0.2061	0.79968	1.2366	0.3807
55	21.414	23.755	26.236	1.896	24.011	26.789	29.823	2.3802	1.8137	3.0338	3.7922	0.81849
100	22.238	23.945	25.041	1.0328	23.64	25.593	26.648	1.1433	0.7831	1.6487	2.4319	0.6079
105	24.011	24.827	26.03	0.87214	28.833	29.798	30.647	0.85853	4.6167	4.9711	5.3998	0.3174

Device Test: 41.13 _SoftStart|ClampVoltage/COMP1/7/7///90.9/634//0///@COMP_V_CLAMP





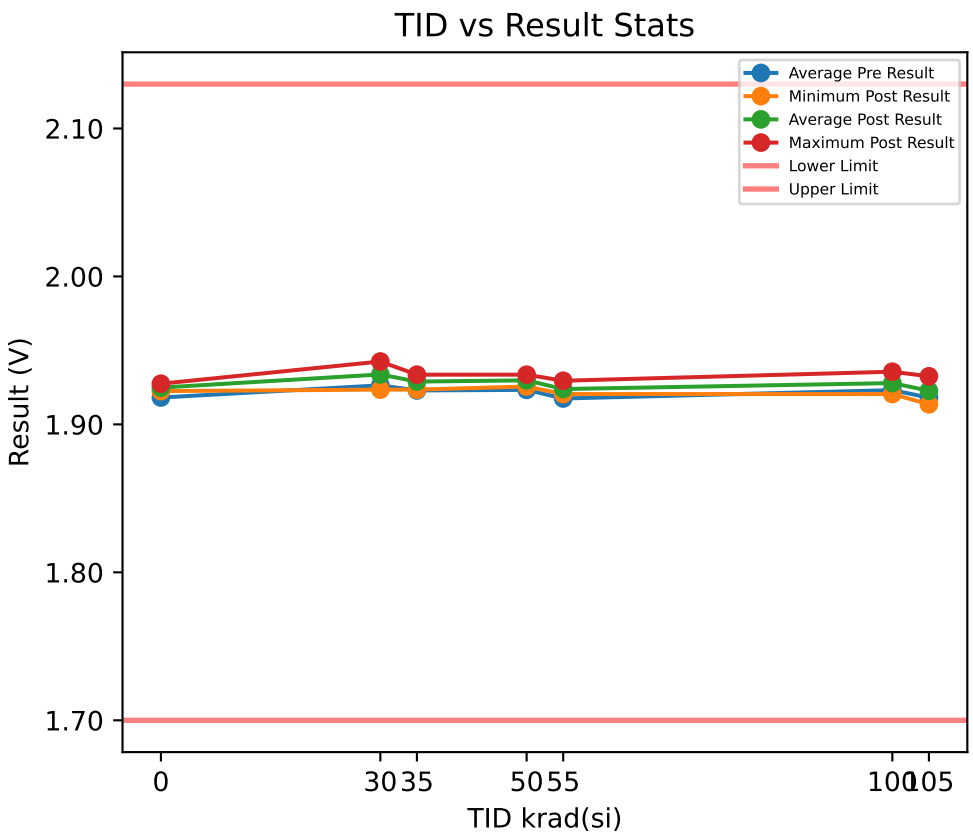
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

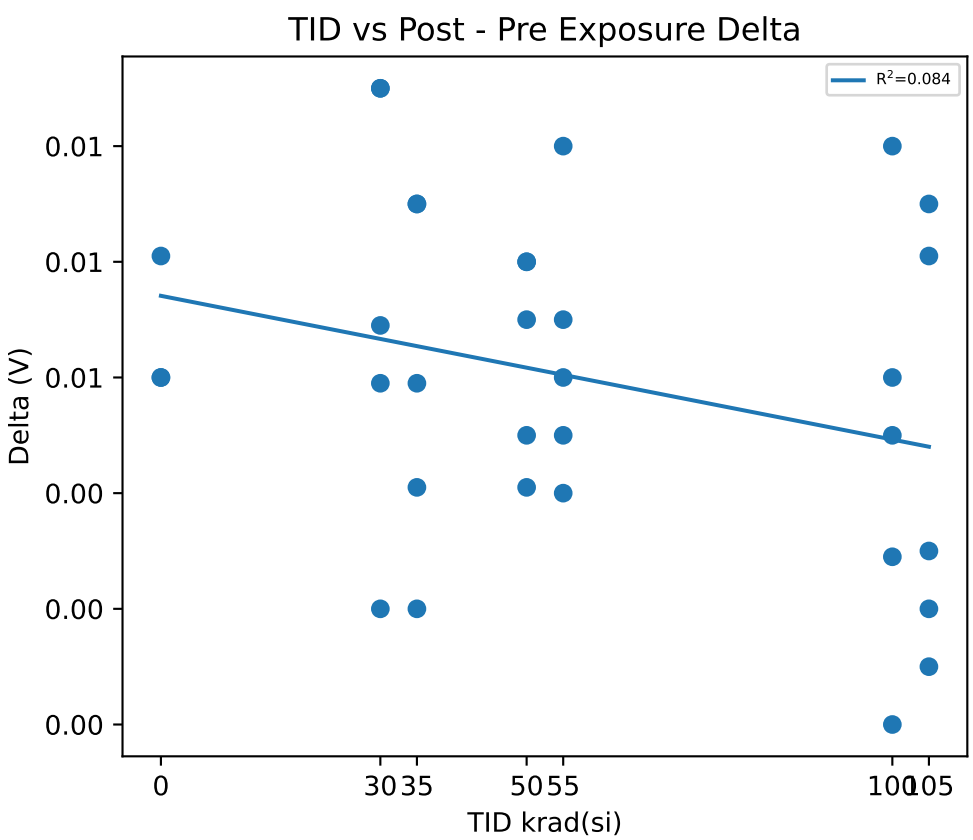
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9215	1.9275	0.006
2	0	CU2	1.9165	1.9225	0.006
3	0	CU3	1.9165	1.9246	0.0081
11	30	Unbiased-30krad	1.9215	1.9235	0.002
12	30	Unbiased-30krad	1.9246	1.9305	0.0059
13	30	Unbiased-30krad	1.9356	1.9425	0.0069
14	30	Unbiased-30krad	1.9256	1.9366	0.011
15	30	Unbiased-30krad	1.9246	1.9356	0.011
16	35	Biased-30krad	1.9215	1.9235	0.002
17	35	Biased-30krad	1.9246	1.9336	0.009
18	35	Biased-30krad	1.9246	1.9305	0.0059
19	35	Biased-30krad	1.9225	1.9315	0.009
20	35	Biased-30krad	1.9215	1.9256	0.0041
30	50	Unbiased-50krad	1.9215	1.9265	0.005
31	50	Unbiased-50krad	1.9256	1.9336	0.008
32	50	Unbiased-50krad	1.9225	1.9295	0.007
33	50	Unbiased-50krad	1.9215	1.9256	0.0041
34	50	Unbiased-50krad	1.9256	1.9336	0.008
40	55	Biased-50krad	1.9225	1.9295	0.007
41	55	Biased-50krad	1.9155	1.9205	0.005
42	55	Biased-50krad	1.9165	1.9225	0.006
43	55	Biased-50krad	1.9165	1.9205	0.004
44	55	Biased-50krad	1.9165	1.9265	0.01
45	100	Unbiased-100krad	1.9246	1.9275	0.0029
46	100	Unbiased-100krad	1.9105	1.9205	0.01
47	100	Unbiased-100krad	1.9356	1.9356	0
48	100	Unbiased-100krad	1.9225	1.9285	0.006
49	100	Unbiased-100krad	1.9225	1.9275	0.005
50	105	Biased-100krad	1.9235	1.9325	0.009
51	105	Biased-100krad	1.9185	1.9215	0.003
52	105	Biased-100krad	1.9215	1.9235	0.002
53	105	Biased-100krad	1.9055	1.9136	0.0081
54	105	Biased-100krad	1.9215	1.9225	0.001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9165	1.9182	1.9215	0.0028868	1.9225	1.9249	1.9275	0.0025106	0.006	0.0067	0.0081	0.0012124
30	1.9215	1.9264	1.9356	0.0053798	1.9235	1.9337	1.9425	0.0071367	0.002	0.00736	0.011	0.0037938
35	1.9215	1.9229	1.9246	0.0015694	1.9235	1.9289	1.9336	0.0042265	0.002	0.006	0.009	0.0030668
50	1.9215	1.9233	1.9256	0.0021031	1.9256	1.9298	1.9336	0.0037912	0.0041	0.00642	0.008	0.0017838
55	1.9155	1.9175	1.9225	0.0028284	1.9205	1.9239	1.9295	0.0039749	0.004	0.0064	0.01	0.0023022
100	1.9105	1.9231	1.9356	0.0089159	1.9205	1.9279	1.9356	0.0053556	0	0.00478	0.01	0.0037138
105	1.9055	1.9181	1.9235	0.0072664	1.9136	1.9227	1.9325	0.0067262	0.001	0.00462	0.009	0.0036704

Device Test: 41.14 _SoftStart|ClampVoltage/COMP2/7/7///90.9/634//0///@COMP_V_CLAMP





Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

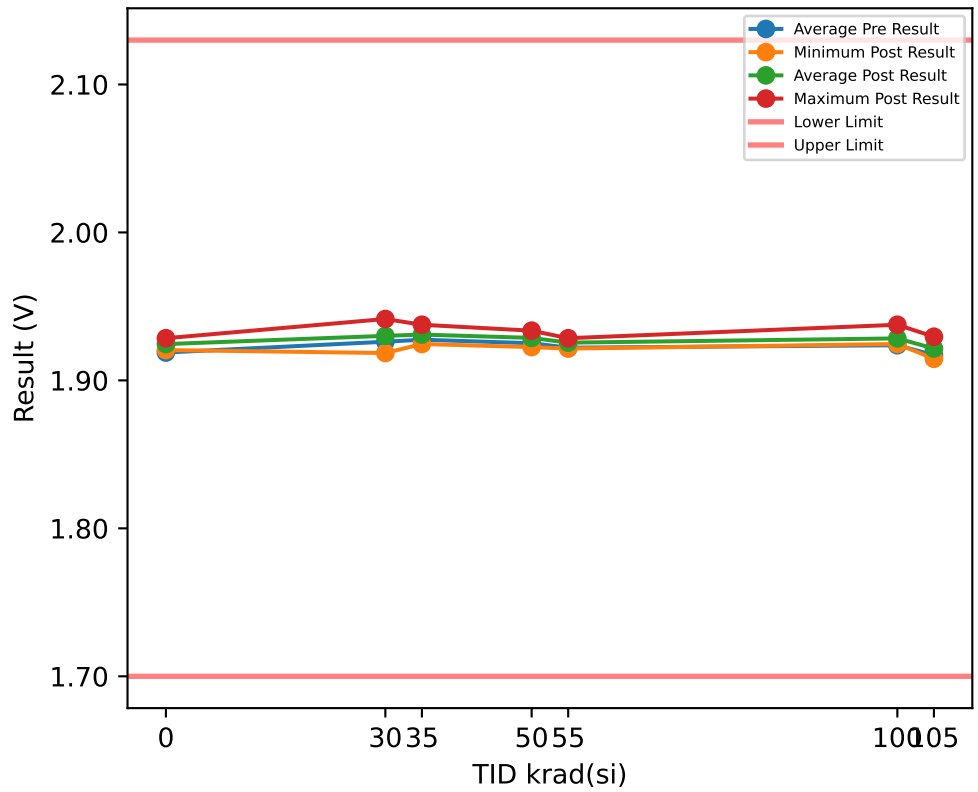
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9215	1.9275	0.006
2	0	CU2	1.9165	1.9225	0.006
3	0	CU3	1.9165	1.9246	0.0081
11	30	Unbiased-30krad	1.9215	1.9235	0.002
12	30	Unbiased-30krad	1.9246	1.9305	0.0059
13	30	Unbiased-30krad	1.9356	1.9425	0.0069
14	30	Unbiased-30krad	1.9256	1.9366	0.011
15	30	Unbiased-30krad	1.9246	1.9356	0.011
16	35	Biased-30krad	1.9215	1.9235	0.002
17	35	Biased-30krad	1.9246	1.9336	0.009
18	35	Biased-30krad	1.9246	1.9305	0.0059
19	35	Biased-30krad	1.9225	1.9315	0.009
20	35	Biased-30krad	1.9215	1.9256	0.0041
30	50	Unbiased-50krad	1.9215	1.9265	0.005
31	50	Unbiased-50krad	1.9256	1.9336	0.008
32	50	Unbiased-50krad	1.9225	1.9295	0.007
33	50	Unbiased-50krad	1.9215	1.9256	0.0041
34	50	Unbiased-50krad	1.9256	1.9336	0.008
40	55	Biased-50krad	1.9225	1.9295	0.007
41	55	Biased-50krad	1.9155	1.9205	0.005
42	55	Biased-50krad	1.9165	1.9225	0.006
43	55	Biased-50krad	1.9165	1.9205	0.004
44	55	Biased-50krad	1.9165	1.9265	0.01
45	100	Unbiased-100krad	1.9246	1.9275	0.0029
46	100	Unbiased-100krad	1.9105	1.9205	0.01
47	100	Unbiased-100krad	1.9356	1.9356	0
48	100	Unbiased-100krad	1.9225	1.9285	0.006
49	100	Unbiased-100krad	1.9225	1.9275	0.005
50	105	Biased-100krad	1.9235	1.9325	0.009
51	105	Biased-100krad	1.9185	1.9215	0.003
52	105	Biased-100krad	1.9215	1.9235	0.002
53	105	Biased-100krad	1.9055	1.9136	0.0081
54	105	Biased-100krad	1.9215	1.9225	0.001

Test Statistics (V)

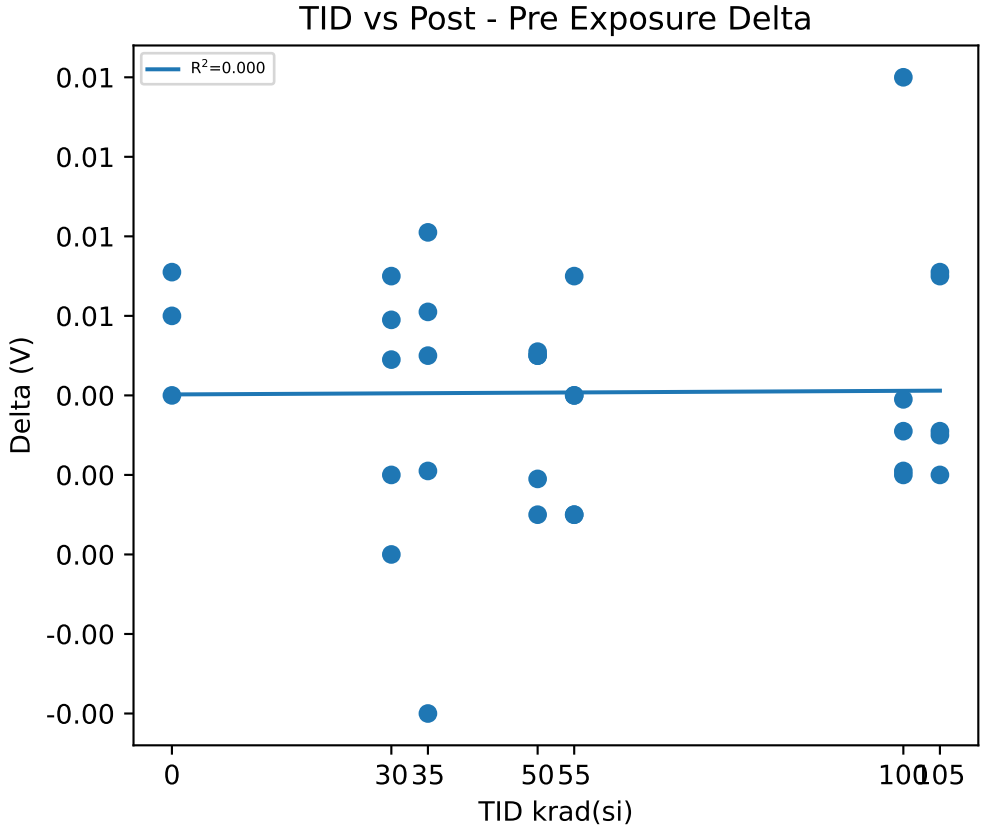
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9165	1.9182	1.9215	0.0028868	1.9225	1.9249	1.9275	0.0025106	0.006	0.0067	0.0081	0.0012124
30	1.9215	1.9264	1.9356	0.0053798	1.9235	1.9337	1.9425	0.0071367	0.002	0.00736	0.011	0.0037938
35	1.9215	1.9229	1.9246	0.0015694	1.9235	1.9289	1.9336	0.0042265	0.002	0.006	0.009	0.0030668
50	1.9215	1.9233	1.9256	0.0021031	1.9256	1.9298	1.9336	0.0037912	0.0041	0.00642	0.008	0.0017838
55	1.9155	1.9175	1.9225	0.0028284	1.9205	1.9239	1.9295	0.0039749	0.004	0.0064	0.01	0.0023022
100	1.9105	1.9231	1.9356	0.0089159	1.9205	1.9279	1.9356	0.0053556	0	0.00478	0.01	0.0037138
105	1.9055	1.9181	1.9235	0.0072664	1.9136	1.9227	1.9325	0.0067262	0.001	0.00462	0.009	0.0036704

Device Test: 41.15 _SoftStart|ClampVoltage/COMP3/7/7///90.9/634//0///@COMP_V_CLAMP

TID vs Result Stats



TID vs Post - Pre Exposure Delta



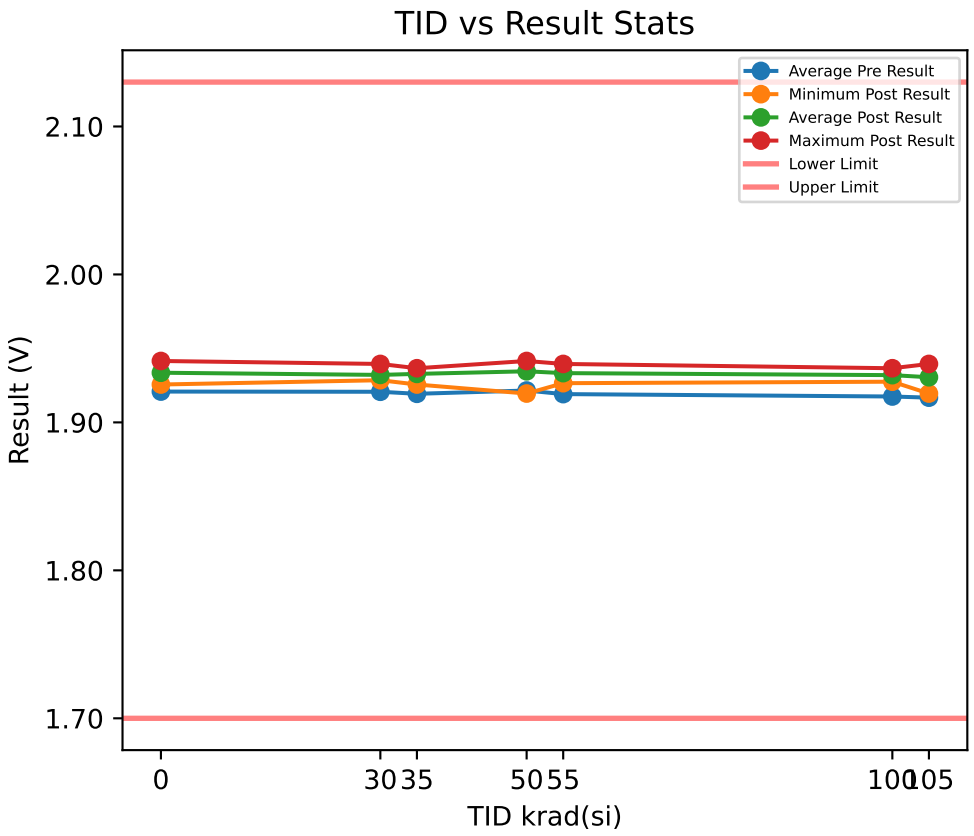
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

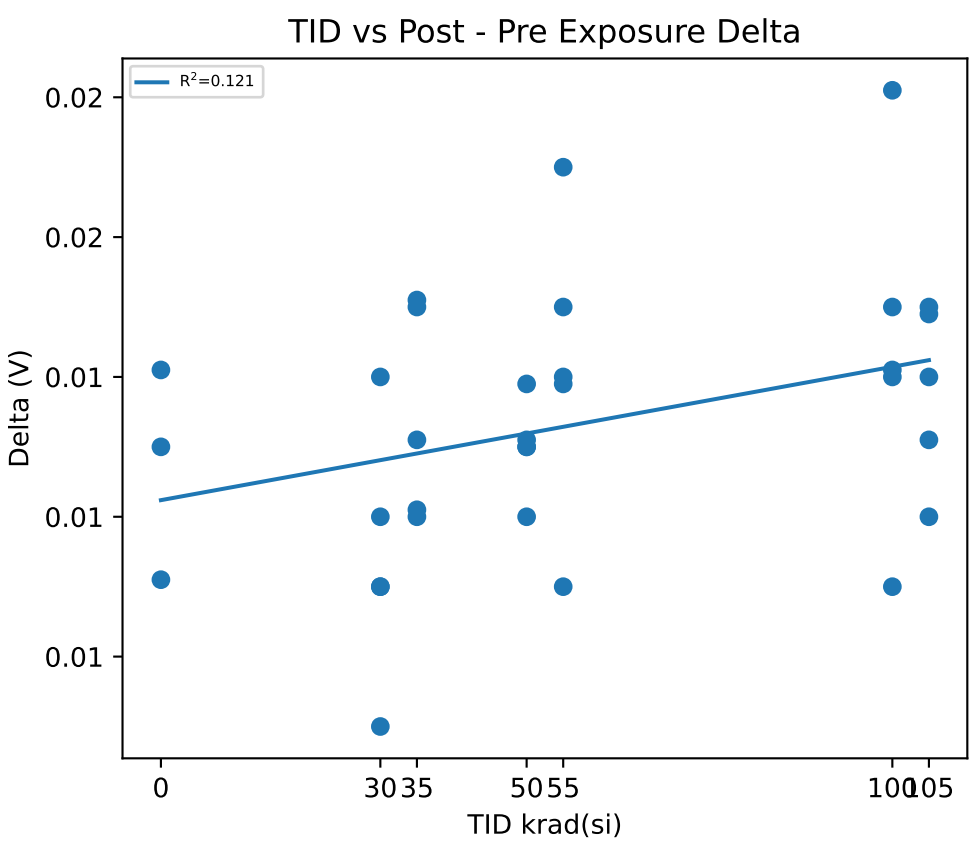
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9225	1.9285	0.006
2	0	CU2	1.9165	1.9205	0.004
3	0	CU3	1.9175	1.9246	0.0071
11	30	Unbiased-30krad	1.9215	1.9215	0
12	30	Unbiased-30krad	1.9315	1.9385	0.007
13	30	Unbiased-30krad	1.9366	1.9415	0.0049
14	30	Unbiased-30krad	1.9246	1.9305	0.0059
15	30	Unbiased-30krad	1.9165	1.9185	0.002
16	35	Biased-30krad	1.9225	1.9246	0.0021
17	35	Biased-30krad	1.9265	1.9346	0.0081
18	35	Biased-30krad	1.9265	1.9315	0.005
19	35	Biased-30krad	1.9315	1.9376	0.0061
20	35	Biased-30krad	1.9305	1.9265	-0.004
30	50	Unbiased-50krad	1.9256	1.9275	0.0019
31	50	Unbiased-50krad	1.9275	1.9325	0.005
32	50	Unbiased-50krad	1.9225	1.9275	0.005
33	50	Unbiased-50krad	1.9215	1.9225	0.001
34	50	Unbiased-50krad	1.9285	1.9336	0.0051
40	55	Biased-50krad	1.9225	1.9265	0.004
41	55	Biased-50krad	1.9265	1.9275	0.001
42	55	Biased-50krad	1.9225	1.9235	0.001
43	55	Biased-50krad	1.9175	1.9215	0.004
44	55	Biased-50krad	1.9215	1.9285	0.007
45	100	Unbiased-100krad	1.9225	1.9246	0.0021
46	100	Unbiased-100krad	1.9136	1.9256	0.012
47	100	Unbiased-100krad	1.9356	1.9376	0.002
48	100	Unbiased-100krad	1.9246	1.9285	0.0039
49	100	Unbiased-100krad	1.9225	1.9256	0.0031
50	105	Biased-100krad	1.9225	1.9295	0.007
51	105	Biased-100krad	1.9165	1.9195	0.003
52	105	Biased-100krad	1.9225	1.9256	0.0031
53	105	Biased-100krad	1.9075	1.9146	0.0071
54	105	Biased-100krad	1.9165	1.9185	0.002

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9165	1.9188	1.9225	0.0032146	1.9205	1.9245	1.9285	0.0040004	0.004	0.0057	0.0071	0.0015716
30	1.9165	1.9261	1.9366	0.0079839	1.9185	1.9301	1.9415	0.010114	0	0.00396	0.007	0.0028902
35	1.9225	1.9275	1.9315	0.0036056	1.9246	1.931	1.9376	0.0054307	-0.004	0.00346	0.0081	0.0047003
50	1.9215	1.9251	1.9285	0.0030532	1.9225	1.9287	1.9336	0.0044656	0.001	0.0036	0.0051	0.0019887
55	1.9175	1.9221	1.9265	0.0032094	1.9215	1.9255	1.9285	0.0029155	0.001	0.0034	0.007	0.00251
100	1.9136	1.9238	1.9356	0.0078628	1.9246	1.9284	1.9376	0.0053565	0.002	0.00462	0.012	0.0041985
105	1.9075	1.9171	1.9225	0.0061482	1.9146	1.9215	1.9295	0.0059458	0.002	0.00444	0.0071	0.0024214

Device Test: 41.16 _SoftStart|ClampVoltage/COMP4/7/7///90.9/634//0///@COMP_V_CLAMP





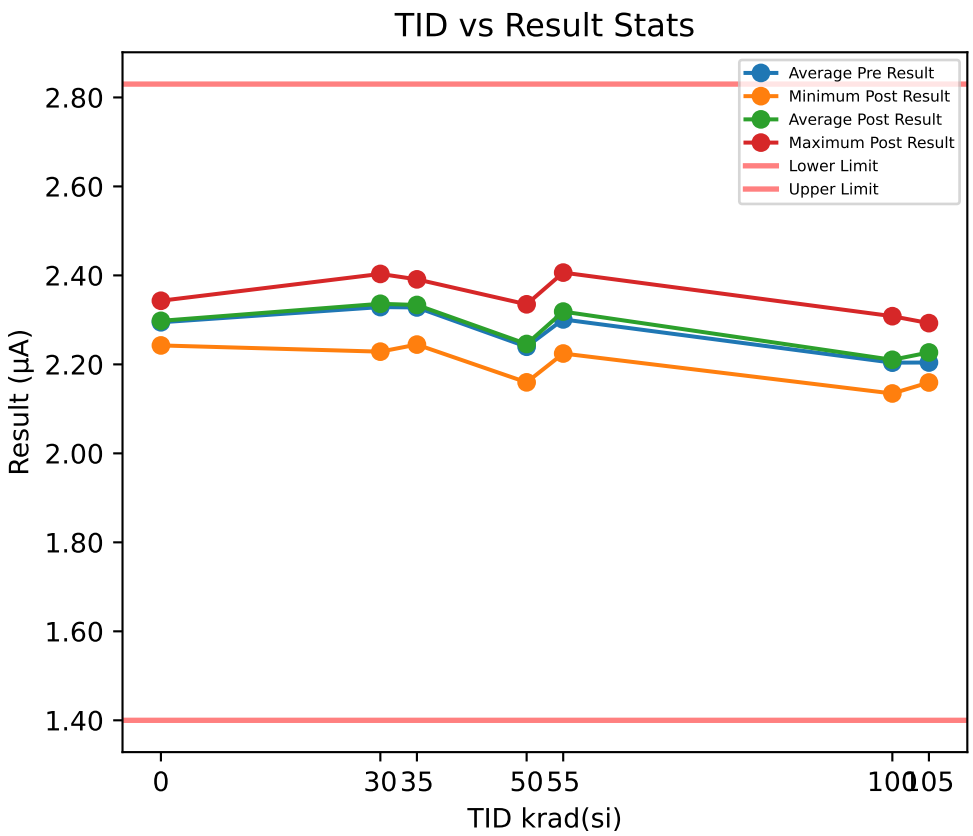
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

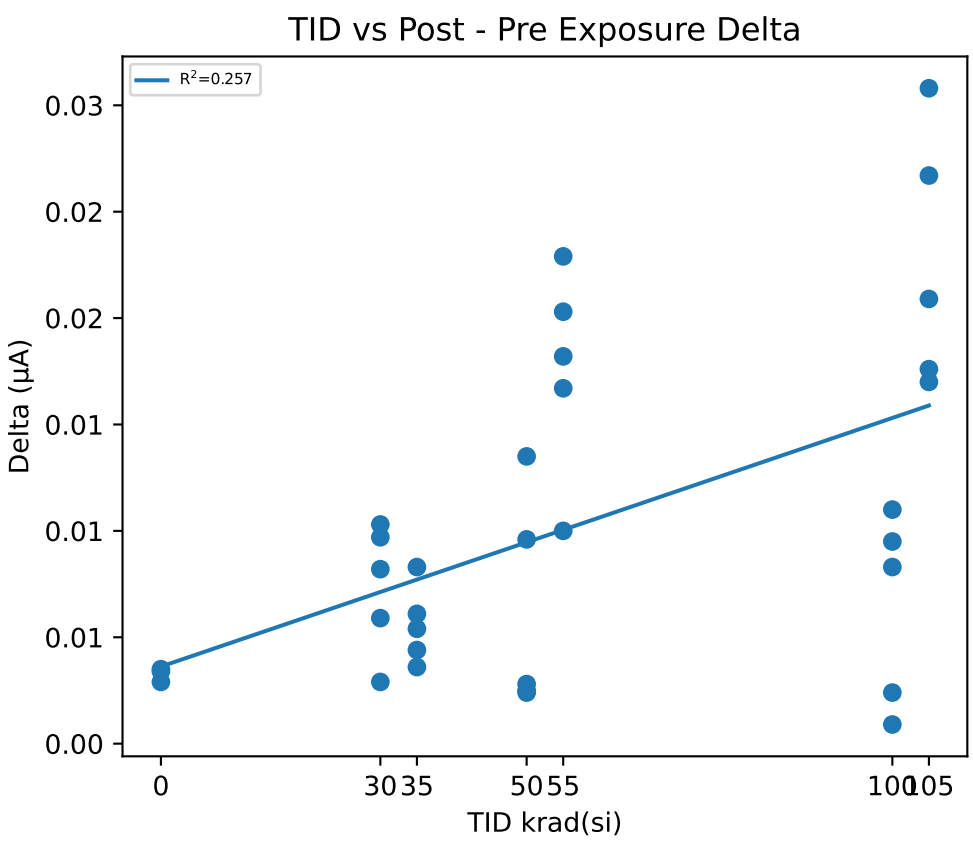
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9285	1.9415	0.013
2	0	CU2	1.9115	1.9256	0.0141
3	0	CU3	1.9225	1.9336	0.0111
11	30	Unbiased-30krad	1.9215	1.9305	0.009
12	30	Unbiased-30krad	1.9165	1.9285	0.012
13	30	Unbiased-30krad	1.9285	1.9395	0.011
14	30	Unbiased-30krad	1.9215	1.9325	0.011
15	30	Unbiased-30krad	1.9155	1.9295	0.014
16	35	Biased-30krad	1.9225	1.9356	0.0131
17	35	Biased-30krad	1.9246	1.9366	0.012
18	35	Biased-30krad	1.9165	1.9315	0.015
19	35	Biased-30krad	1.9225	1.9346	0.0121
20	35	Biased-30krad	1.9105	1.9256	0.0151
30	50	Unbiased-50krad	1.9075	1.9195	0.012
31	50	Unbiased-50krad	1.9246	1.9385	0.0139
32	50	Unbiased-50krad	1.9225	1.9356	0.0131
33	50	Unbiased-50krad	1.9285	1.9415	0.013
34	50	Unbiased-50krad	1.9246	1.9376	0.013
40	55	Biased-50krad	1.9165	1.9305	0.014
41	55	Biased-50krad	1.9165	1.9315	0.015
42	55	Biased-50krad	1.9225	1.9395	0.017
43	55	Biased-50krad	1.9155	1.9265	0.011
44	55	Biased-50krad	1.9246	1.9385	0.0139
45	100	Unbiased-100krad	1.9165	1.9305	0.014
46	100	Unbiased-100krad	1.9155	1.9305	0.015
47	100	Unbiased-100krad	1.9165	1.9275	0.011
48	100	Unbiased-100krad	1.9165	1.9346	0.0181
49	100	Unbiased-100krad	1.9225	1.9366	0.0141
50	105	Biased-100krad	1.9215	1.9346	0.0131
51	105	Biased-100krad	1.9246	1.9395	0.0149
52	105	Biased-100krad	1.9055	1.9195	0.014
53	105	Biased-100krad	1.9155	1.9305	0.015
54	105	Biased-100krad	1.9165	1.9285	0.012

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9115	1.9208	1.9285	0.0086217	1.9256	1.9336	1.9415	0.0079501	0.0111	0.012733	0.0141	0.0015177
30	1.9155	1.9207	1.9285	0.0051672	1.9285	1.9321	1.9395	0.0043932	0.009	0.0114	0.014	0.0018166
35	1.9105	1.9193	1.9246	0.0057846	1.9256	1.9328	1.9366	0.0044454	0.012	0.01346	0.0151	0.0015143
50	1.9075	1.9215	1.9285	0.0081427	1.9195	1.9345	1.9415	0.008672	0.012	0.013	0.0139	0.00067454
55	1.9155	1.9191	1.9246	0.0041318	1.9265	1.9333	1.9395	0.0055408	0.011	0.01418	0.017	0.0021707
100	1.9155	1.9175	1.9225	0.0028284	1.9275	1.9319	1.9366	0.0036281	0.011	0.01444	0.0181	0.0025422
105	1.9055	1.9167	1.9246	0.0072864	1.9195	1.9305	1.9395	0.0074634	0.012	0.0138	0.015	0.0012669

Device Test: 41.2 _SoftStart|ChargeCurrent/SS2/7/7///90.9/634//0///@I_SS





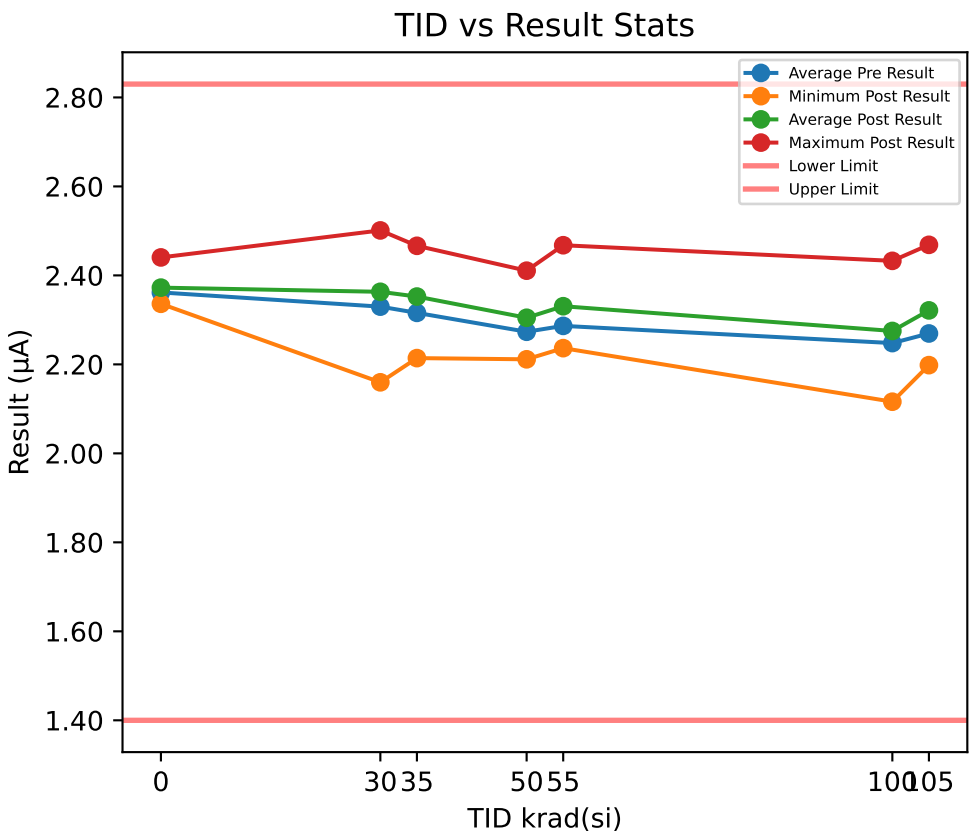
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

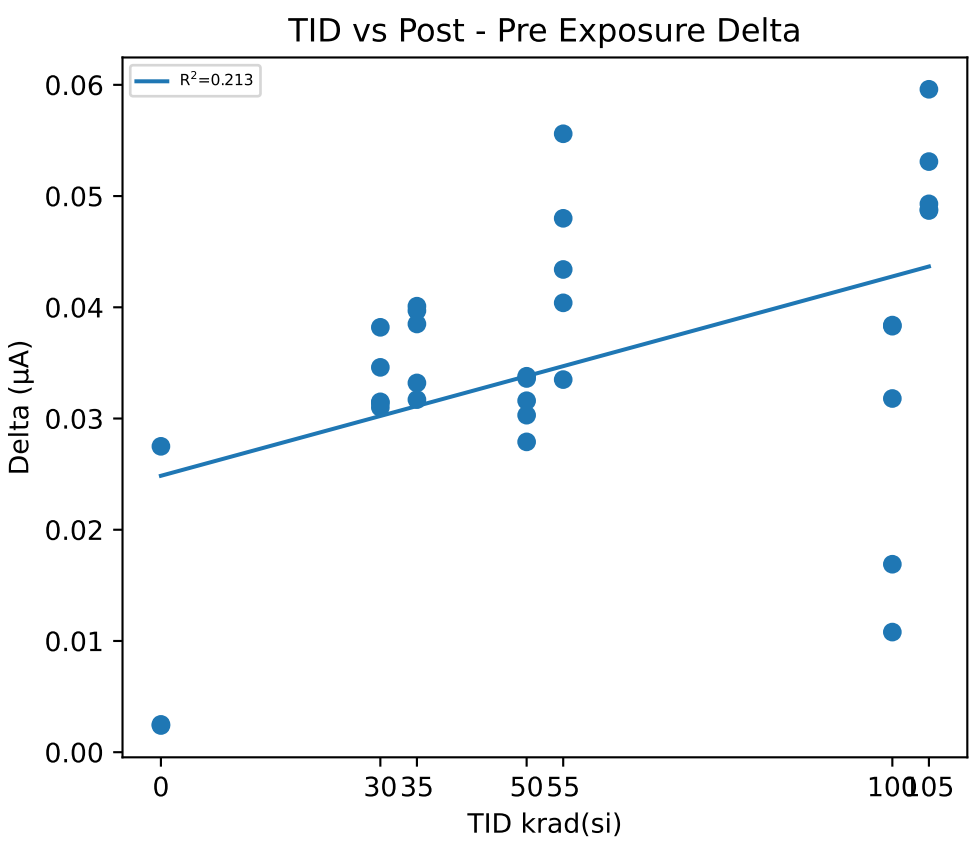
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3401	2.343	0.0029
2	0	CU2	2.2391	2.2426	0.0035
3	0	CU3	2.3046	2.308	0.0034
11	30	Unbiased-30krad	2.3746	2.3828	0.0082
12	30	Unbiased-30krad	2.3927	2.3956	0.0029
13	30	Unbiased-30krad	2.3936	2.4033	0.0097
14	30	Unbiased-30krad	2.2227	2.2286	0.0059
15	30	Unbiased-30krad	2.2603	2.2706	0.0103
16	35	Biased-30krad	2.3287	2.337	0.0083
17	35	Biased-30krad	2.379	2.3826	0.0036
18	35	Biased-30krad	2.308	2.3124	0.0044
19	35	Biased-30krad	2.3857	2.3911	0.0054
20	35	Biased-30krad	2.2384	2.2445	0.0061
30	50	Unbiased-50krad	2.2103	2.2199	0.0096
31	50	Unbiased-50krad	2.3326	2.335	0.0024
32	50	Unbiased-50krad	2.2001	2.2136	0.0135
33	50	Unbiased-50krad	2.1568	2.1596	0.0028
34	50	Unbiased-50krad	2.2985	2.301	0.0025
40	55	Biased-50krad	2.3077	2.328	0.0203
41	55	Biased-50krad	2.37	2.38	0.01
42	55	Biased-50krad	2.3896	2.4063	0.0167
43	55	Biased-50krad	2.2318	2.2547	0.0229
44	55	Biased-50krad	2.2062	2.2244	0.0182
45	100	Unbiased-100krad	2.1776	2.1785	0.0009
46	100	Unbiased-100krad	2.1251	2.1346	0.0095
47	100	Unbiased-100krad	2.2297	2.2321	0.0024
48	100	Unbiased-100krad	2.3	2.3083	0.0083
49	100	Unbiased-100krad	2.187	2.198	0.011
50	105	Biased-100krad	2.2453	2.2629	0.0176
51	105	Biased-100krad	2.1595	2.1903	0.0308
52	105	Biased-100krad	2.2118	2.2288	0.017
53	105	Biased-100krad	2.1326	2.1593	0.0267
54	105	Biased-100krad	2.2718	2.2927	0.0209

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2391	2.2946	2.3401	0.051237	2.2426	2.2979	2.343	0.050961	0.0029	0.0032667	0.0035	0.00032146
30	2.2227	2.3288	2.3936	0.081132	2.2286	2.3362	2.4033	0.080752	0.0029	0.0074	0.0103	0.0030348
35	2.2384	2.328	2.3857	0.059914	2.2445	2.3335	2.3911	0.059387	0.0036	0.00556	0.0083	0.0018036
50	2.1568	2.2397	2.3326	0.073131	2.1596	2.2458	2.335	0.070961	0.0024	0.00616	0.0135	0.005112
55	2.2062	2.3011	2.3896	0.081289	2.2244	2.3187	2.4063	0.078273	0.01	0.01762	0.0229	0.0048556
100	2.1251	2.2039	2.3	0.06536	2.1346	2.2103	2.3083	0.065139	0.0009	0.00642	0.011	0.0044897
105	2.1326	2.2042	2.2718	0.057968	2.1593	2.2268	2.2927	0.053709	0.017	0.0226	0.0308	0.0059854

Device Test: 41.3 _SoftStart|ChargeCurrent/SS3/7/7///90.9/634//0///@I_SS





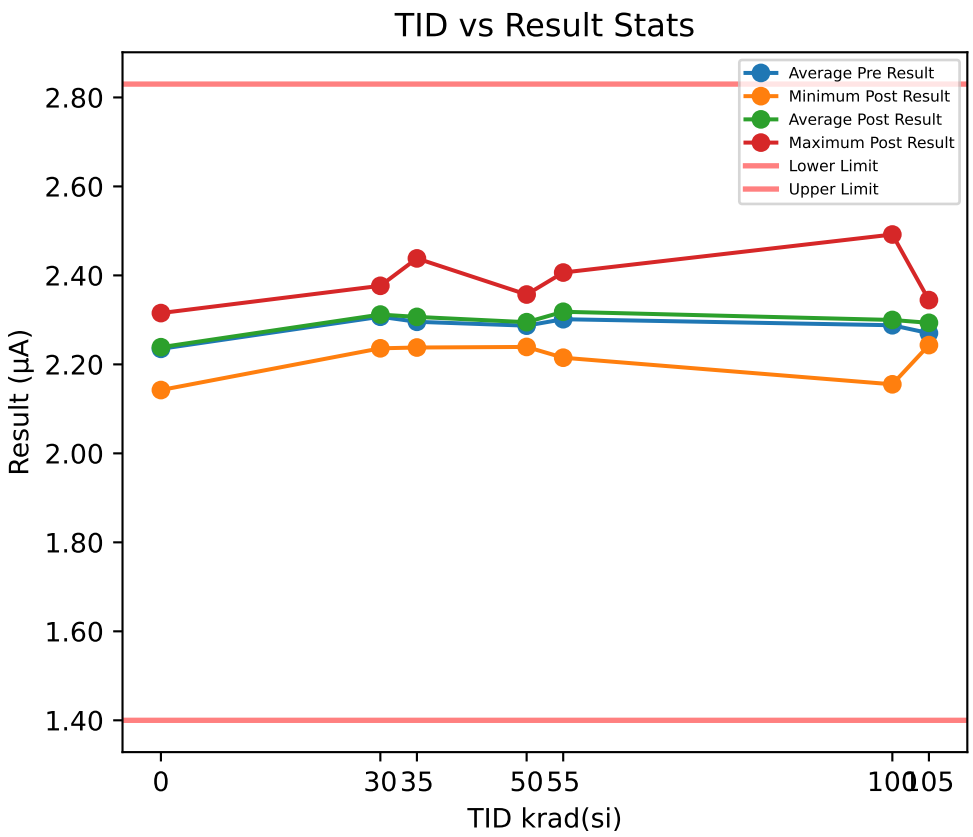
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

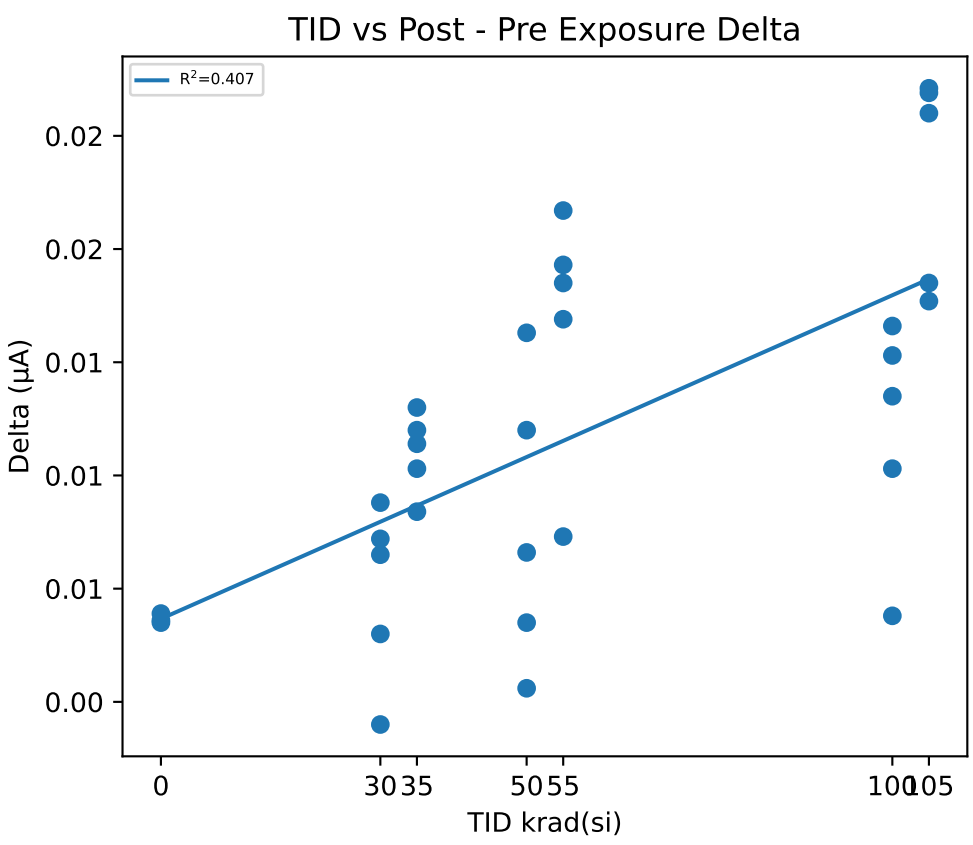
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4379	2.4404	0.0025
2	0	CU2	2.3338	2.3362	0.0024
3	0	CU3	2.3134	2.3409	0.0275
11	30	Unbiased-30krad	2.3271	2.3586	0.0315
12	30	Unbiased-30krad	2.3845	2.4155	0.031
13	30	Unbiased-30krad	2.4629	2.5011	0.0382
14	30	Unbiased-30krad	2.1251	2.1597	0.0346
15	30	Unbiased-30krad	2.3494	2.3808	0.0314
16	35	Biased-30krad	2.2923	2.3255	0.0332
17	35	Biased-30krad	2.3444	2.3841	0.0397
18	35	Biased-30krad	2.3403	2.372	0.0317
19	35	Biased-30krad	2.4264	2.4665	0.0401
20	35	Biased-30krad	2.1756	2.2141	0.0385
30	50	Unbiased-50krad	2.1798	2.2114	0.0316
31	50	Unbiased-50krad	2.2112	2.2391	0.0279
32	50	Unbiased-50krad	2.2724	2.3027	0.0303
33	50	Unbiased-50krad	2.3768	2.4106	0.0338
34	50	Unbiased-50krad	2.3264	2.36	0.0336
40	55	Biased-50krad	2.3267	2.3602	0.0335
41	55	Biased-50krad	2.2715	2.3119	0.0404
42	55	Biased-50krad	2.4122	2.4678	0.0556
43	55	Biased-50krad	2.1885	2.2365	0.048
44	55	Biased-50krad	2.2338	2.2772	0.0434
45	100	Unbiased-100krad	2.2083	2.2401	0.0318
46	100	Unbiased-100krad	2.0992	2.1161	0.0169
47	100	Unbiased-100krad	2.2495	2.2878	0.0383
48	100	Unbiased-100krad	2.3943	2.4327	0.0384
49	100	Unbiased-100krad	2.2881	2.2989	0.0108
50	105	Biased-100krad	2.42	2.4687	0.0487
51	105	Biased-100krad	2.1923	2.2411	0.0488
52	105	Biased-100krad	2.293	2.3526	0.0596
53	105	Biased-100krad	2.1452	2.1983	0.0531
54	105	Biased-100krad	2.2968	2.3461	0.0493

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3134	2.3617	2.4379	0.066775	2.3362	2.3725	2.4404	0.05885	0.0024	0.0108	0.0275	0.014463
30	2.1251	2.3298	2.4629	0.1255	2.1597	2.3631	2.5011	0.12599	0.031	0.03334	0.0382	0.0030754
35	2.1756	2.3158	2.4264	0.092004	2.2141	2.3524	2.4665	0.092545	0.0317	0.03664	0.0401	0.0039061
50	2.1798	2.2733	2.3768	0.080826	2.2114	2.3048	2.4106	0.082591	0.0279	0.03144	0.0338	0.0024542
55	2.1885	2.2865	2.4122	0.086635	2.2365	2.3307	2.4678	0.089101	0.0335	0.04418	0.0556	0.008276
100	2.0992	2.2479	2.3943	0.10809	2.1161	2.2751	2.4327	0.1141	0.0108	0.02724	0.0384	0.012697
105	2.1452	2.2695	2.42	0.10649	2.1983	2.3214	2.4687	0.10593	0.0487	0.0519	0.0596	0.0046728

Device Test: 41.4 _SoftStart|ChargeCurrent/SS4/7/7///90.9/634//0///@I_SS





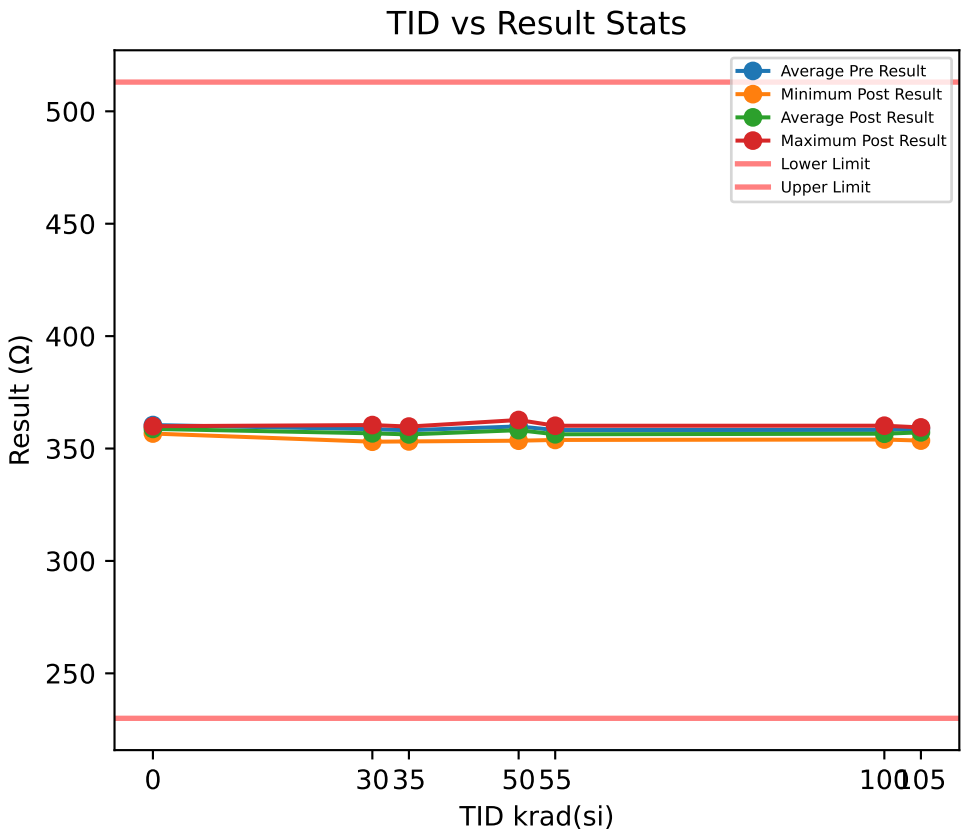
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

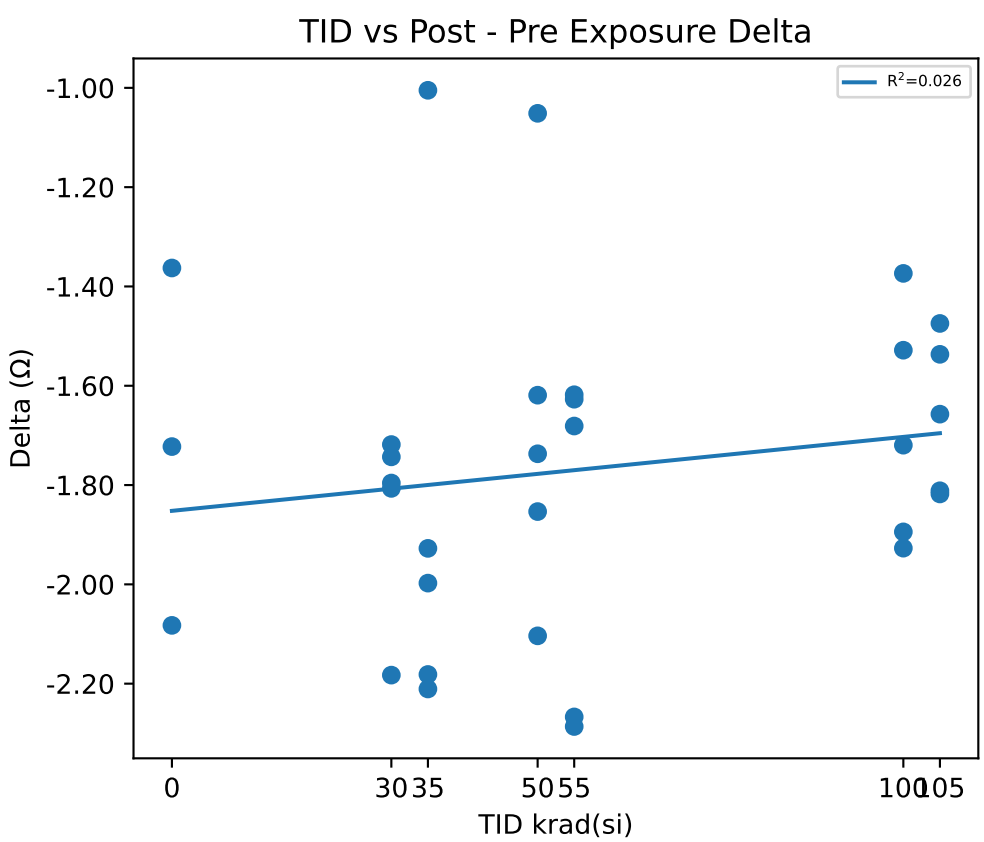
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3118	2.3153	0.0035
2	0	CU2	2.1387	2.1423	0.0036
3	0	CU3	2.2543	2.2582	0.0039
11	30	Unbiased-30krad	2.3473	2.3545	0.0072
12	30	Unbiased-30krad	2.297	2.3	0.003
13	30	Unbiased-30krad	2.3678	2.3766	0.0088
14	30	Unbiased-30krad	2.2936	2.2926	-0.001
15	30	Unbiased-30krad	2.2296	2.2361	0.0065
16	35	Biased-30krad	2.2959	2.3089	0.013
17	35	Biased-30krad	2.2276	2.2379	0.0103
18	35	Biased-30krad	2.2905	2.2989	0.0084
19	35	Biased-30krad	2.4262	2.4382	0.012
20	35	Biased-30krad	2.2383	2.2497	0.0114
30	50	Unbiased-50krad	2.2432	2.2467	0.0035
31	50	Unbiased-50krad	2.3504	2.357	0.0066
32	50	Unbiased-50krad	2.2872	2.2992	0.012
33	50	Unbiased-50krad	2.2386	2.2392	0.0006
34	50	Unbiased-50krad	2.3157	2.332	0.0163
40	55	Biased-50krad	2.3208	2.3281	0.0073
41	55	Biased-50krad	2.3895	2.4064	0.0169
42	55	Biased-50krad	2.3093	2.3286	0.0193
43	55	Biased-50krad	2.2947	2.3132	0.0185
44	55	Biased-50krad	2.1933	2.215	0.0217
45	100	Unbiased-100krad	2.3018	2.3056	0.0038
46	100	Unbiased-100krad	2.1386	2.1552	0.0166
47	100	Unbiased-100krad	2.3358	2.3493	0.0135
48	100	Unbiased-100krad	2.4766	2.4919	0.0153
49	100	Unbiased-100krad	2.1869	2.1972	0.0103
50	105	Biased-100krad	2.2485	2.2754	0.0269
51	105	Biased-100krad	2.2174	2.2434	0.026
52	105	Biased-100krad	2.326	2.3445	0.0185
53	105	Biased-100krad	2.2805	2.3076	0.0271
54	105	Biased-100krad	2.2784	2.2961	0.0177

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1387	2.2349	2.3118	0.08816	2.1423	2.2386	2.3153	0.08815	0.0035	0.0036667	0.0039	0.00020817
30	2.2296	2.3071	2.3678	0.053831	2.2361	2.312	2.3766	0.055364	-0.001	0.0049	0.0088	0.0039205
35	2.2276	2.2957	2.4262	0.079041	2.2379	2.3067	2.4382	0.079593	0.0084	0.01102	0.013	0.0017612
50	2.2386	2.287	2.3504	0.047708	2.2392	2.2948	2.357	0.051665	0.0006	0.0078	0.0163	0.0063573
55	2.1933	2.3015	2.3895	0.070588	2.215	2.3183	2.4064	0.068302	0.0073	0.01674	0.0217	0.0055541
100	2.1386	2.2879	2.4766	0.13284	2.1552	2.2998	2.4919	0.13306	0.0038	0.0119	0.0166	0.0051083
105	2.2174	2.2702	2.326	0.040453	2.2434	2.2934	2.3445	0.037564	0.0177	0.02324	0.0271	0.0047189

Device Test: 41.5 _SoftStart|Resistance/SS1/7/7///90.9/634//0///@R_SS_DISCHARGE





Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

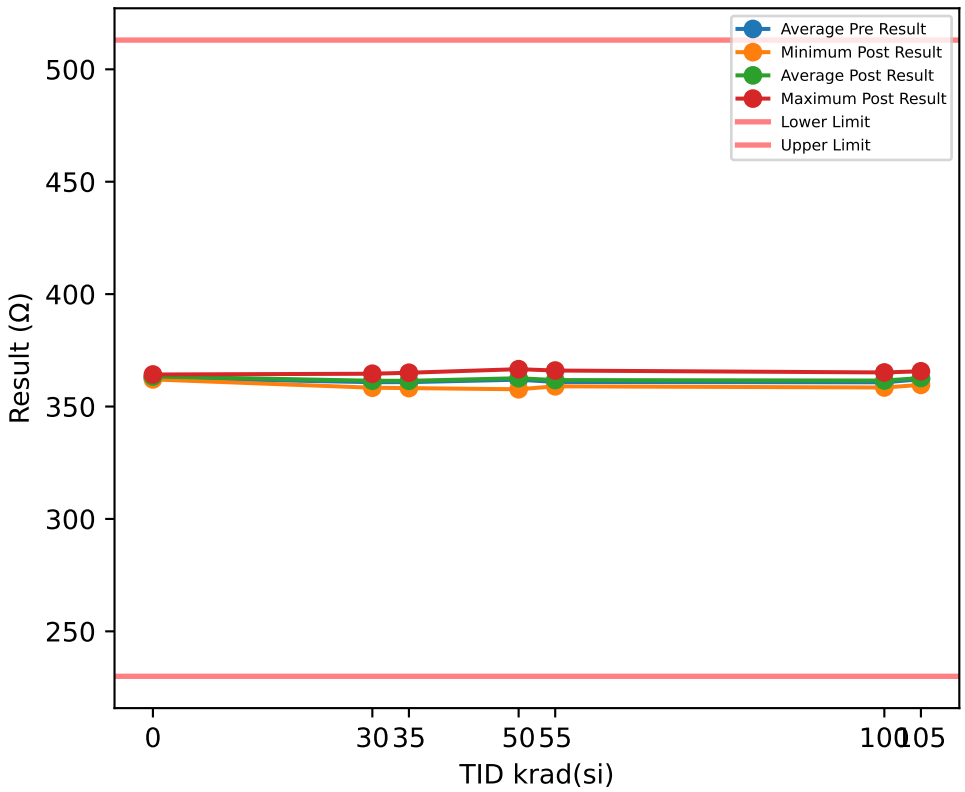
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	362.02	359.94	-2.0826
2	0	CU2	358.03	356.67	-1.3628
3	0	CU3	361.29	359.57	-1.7225
11	30	Unbiased-30krad	355.94	354.13	-1.8067
12	30	Unbiased-30krad	360.45	358.66	-1.7959
13	30	Unbiased-30krad	354.75	353.03	-1.7184
14	30	Unbiased-30krad	359.25	357.51	-1.7432
15	30	Unbiased-30krad	362.62	360.44	-2.1828
16	35	Biased-30krad	361.07	358.89	-2.1815
17	35	Biased-30krad	357.37	355.37	-1.9975
18	35	Biased-30krad	361.98	359.77	-2.2107
19	35	Biased-30krad	355.19	354.18	-1.0049
20	35	Biased-30krad	355.09	353.17	-1.9275
30	50	Unbiased-50krad	359.53	357.79	-1.737
31	50	Unbiased-50krad	355.34	353.48	-1.8534
32	50	Unbiased-50krad	361.76	359.66	-2.1037
33	50	Unbiased-50krad	358.84	357.22	-1.619
34	50	Unbiased-50krad	363.74	362.69	-1.0513
40	55	Biased-50krad	356.36	354.74	-1.6181
41	55	Biased-50krad	357.41	355.14	-2.267
42	55	Biased-50krad	361.76	360.13	-1.6271
43	55	Biased-50krad	360.11	357.83	-2.2863
44	55	Biased-50krad	355.5	353.82	-1.6811
45	100	Unbiased-100krad	355.73	354.01	-1.7197
46	100	Unbiased-100krad	359.77	357.85	-1.9271
47	100	Unbiased-100krad	356.97	355.08	-1.8943
48	100	Unbiased-100krad	357.38	355.85	-1.5284
49	100	Unbiased-100krad	361.53	360.15	-1.3737
50	105	Biased-100krad	360.82	359.35	-1.4745
51	105	Biased-100krad	355.19	353.53	-1.6572
52	105	Biased-100krad	360.65	358.84	-1.8115
53	105	Biased-100krad	356.38	354.85	-1.5367
54	105	Biased-100krad	361.21	359.39	-1.8179

Test Statistics (Ω)

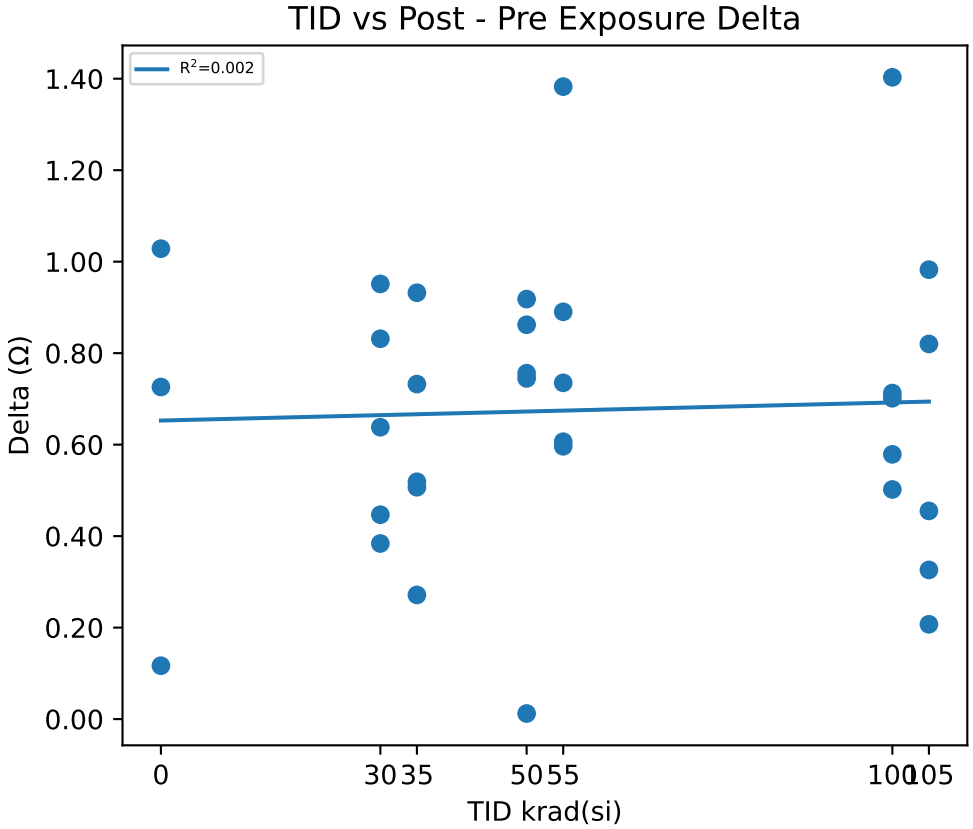
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	358.03	360.45	362.02	2.1237	356.67	358.73	359.94	1.7901	-2.0826	-1.7226	-1.3628	0.3599
30	354.75	358.6	362.62	3.2375	353.03	356.75	360.44	3.1019	-2.1828	-1.8494	-1.7184	0.18992
35	355.09	358.14	361.98	3.24	353.17	356.28	359.77	2.9138	-2.2107	-1.8644	-1.0049	0.49521
50	355.34	359.84	363.74	3.1741	353.48	358.17	362.69	3.3788	-2.1037	-1.6729	-1.0513	0.39101
55	355.5	358.23	361.76	2.6299	353.82	356.33	360.13	2.5969	-2.2863	-1.8959	-1.6181	0.34846
100	355.73	358.28	361.53	2.3355	354.01	356.59	360.15	2.4384	-1.9271	-1.6886	-1.3737	0.23716
105	355.19	358.85	361.21	2.8382	353.53	357.19	359.39	2.7897	-1.8179	-1.6596	-1.4745	0.15613

Device Test: 41.6 _SoftStart|Resistance/SS2/7/7///90.9/634//0///@R_SS_DISCHARGE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

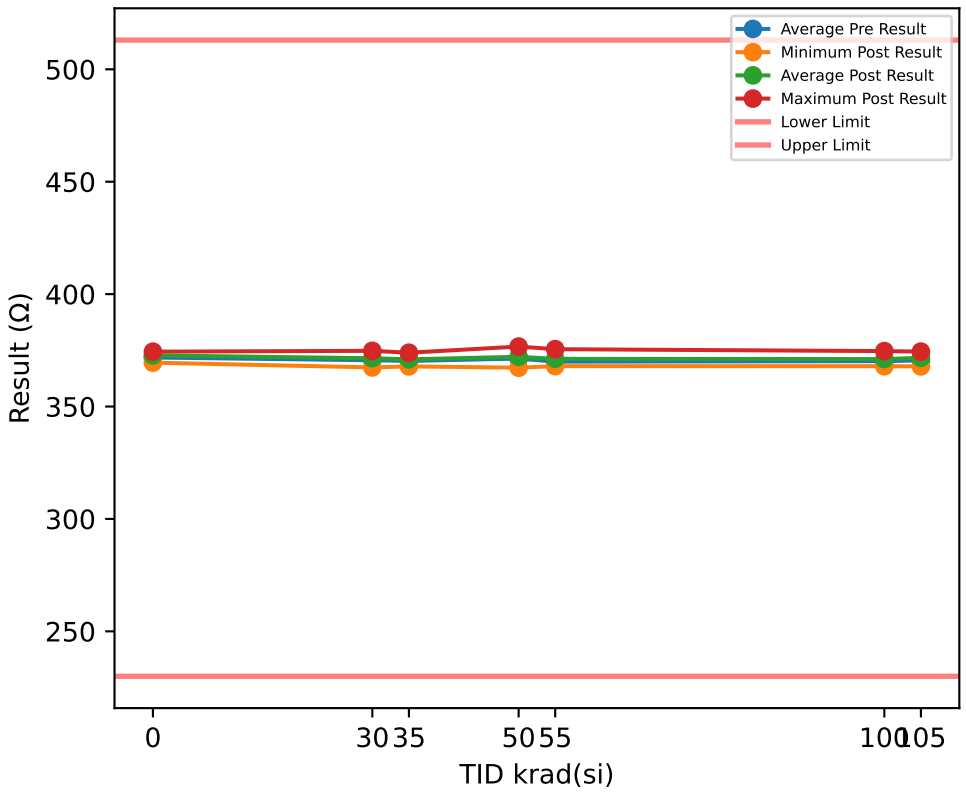
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	364.14	364.25	0.1167
2	0	CU2	361.03	362.06	1.0284
3	0	CU3	363.01	363.74	0.726
11	30	Unbiased-30krad	358.54	358.92	0.3839
12	30	Unbiased-30krad	363.16	363.99	0.8315
13	30	Unbiased-30krad	357.73	358.36	0.6381
14	30	Unbiased-30krad	361.07	361.51	0.4468
15	30	Unbiased-30krad	363.64	364.59	0.9514
16	35	Biased-30krad	363.68	364.19	0.5069
17	35	Biased-30krad	360.32	360.59	0.2714
18	35	Biased-30krad	364.29	365.03	0.7324
19	35	Biased-30krad	358.27	359.2	0.9321
20	35	Biased-30krad	357.69	358.2	0.5188
30	50	Unbiased-50krad	361.93	362.68	0.7448
31	50	Unbiased-50krad	357.66	357.67	0.0122
32	50	Unbiased-50krad	363.07	363.94	0.8621
33	50	Unbiased-50krad	361.32	362.08	0.7562
34	50	Unbiased-50krad	365.7	366.62	0.9182
40	55	Biased-50krad	359.4	360	0.5964
41	55	Biased-50krad	360.21	360.81	0.6064
42	55	Biased-50krad	364.63	366.01	1.3827
43	55	Biased-50krad	362.17	363.06	0.8904
44	55	Biased-50krad	358.26	358.99	0.7351
45	100	Unbiased-100krad	357.96	358.46	0.502
46	100	Unbiased-100krad	362.4	363.11	0.7128
47	100	Unbiased-100krad	359.73	360.31	0.5788
48	100	Unbiased-100krad	359.33	360.73	1.4031
49	100	Unbiased-100krad	364.46	365.16	0.7014
50	105	Biased-100krad	364.06	364.27	0.2072
51	105	Biased-100krad	358.81	359.63	0.8201
52	105	Biased-100krad	362.46	363.44	0.9825
53	105	Biased-100krad	359.98	360.44	0.4551
54	105	Biased-100krad	365.35	365.67	0.3261

Test Statistics (Ω)

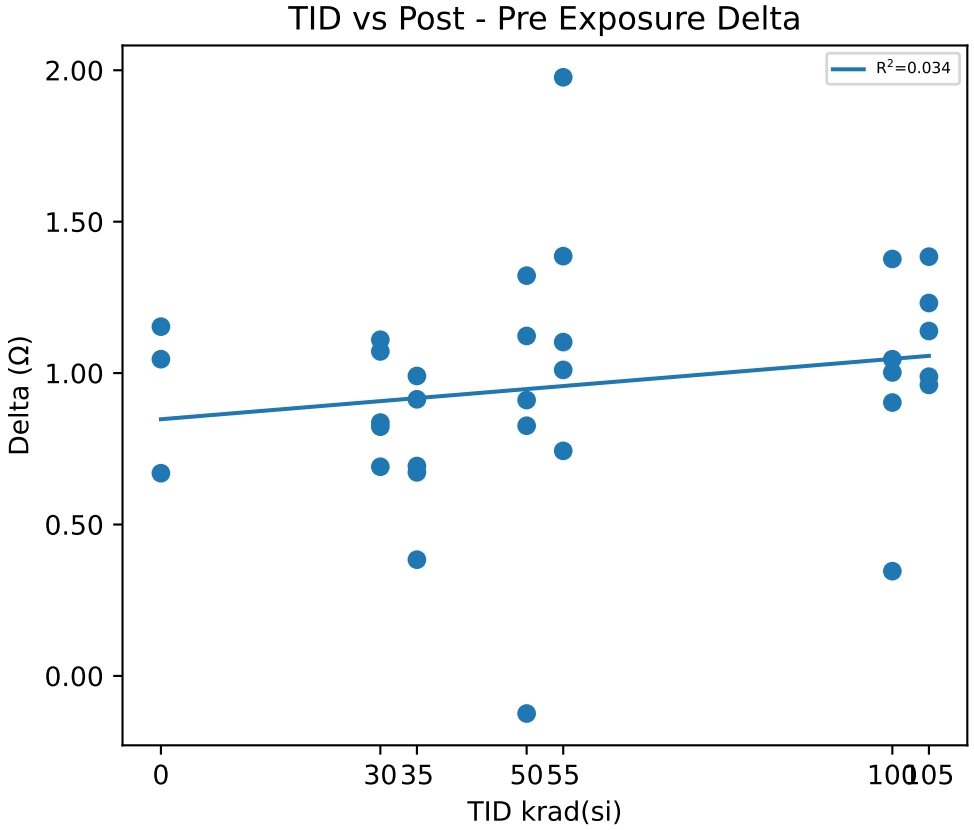
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	361.03	362.73	364.14	1.57	362.06	363.35	364.25	1.145	0.1167	0.6237	1.0284	0.46438
30	357.73	360.83	363.64	2.6574	358.36	361.48	364.59	2.838	0.3839	0.65034	0.9514	0.24291
35	357.69	360.85	364.29	3.0344	358.2	361.44	365.03	3.0254	0.2714	0.59232	0.9321	0.25038
50	357.66	361.94	365.7	2.9218	357.67	362.6	366.62	3.2603	0.0122	0.6587	0.9182	0.36864
55	358.26	360.93	364.63	2.5126	358.99	361.78	366.01	2.8045	0.5964	0.8422	1.3827	0.32479
100	357.96	360.78	364.46	2.6131	358.46	361.56	365.16	2.6083	0.502	0.77962	1.4031	0.35941
105	358.81	362.13	365.35	2.7318	359.63	362.69	365.67	2.5701	0.2072	0.5582	0.9825	0.33027

Device Test: 41.7 _SoftStart|Resistance/SS3/7/7///90.9/634//0///@R_SS_DISCHARGE

TID vs Result Stats



TID vs Post - Pre Exposure Delta



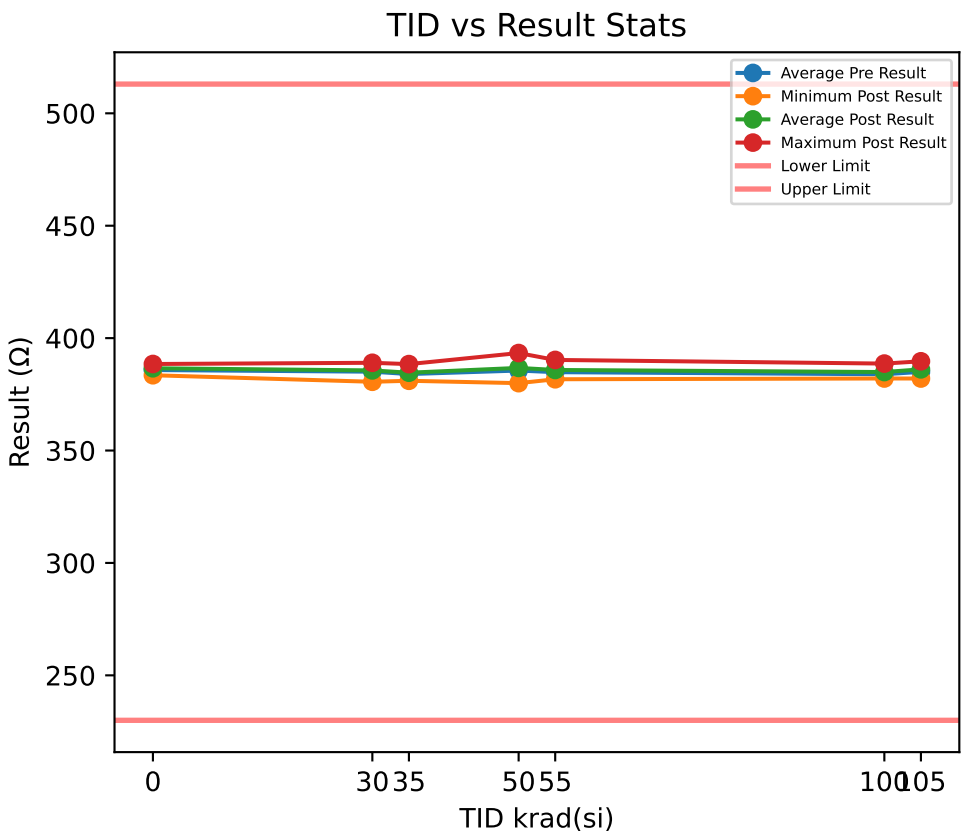
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

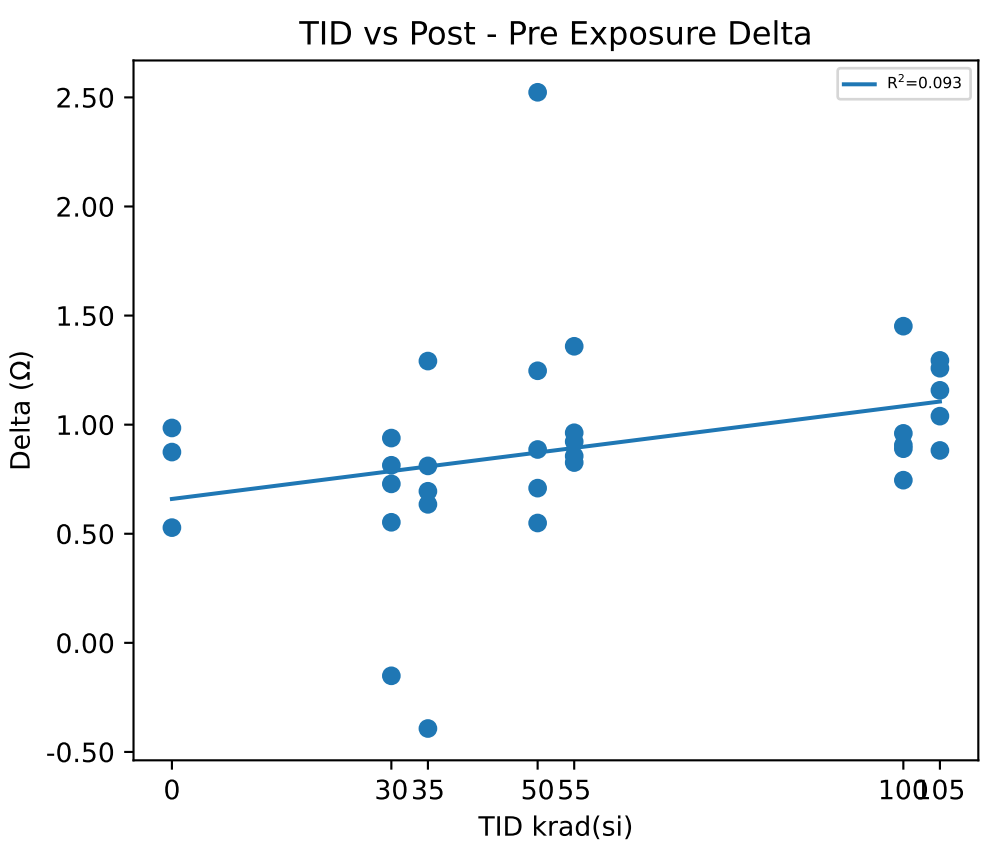
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	373.74	374.41	0.6694
2	0	CU2	368.47	369.51	1.0459
3	0	CU3	373.19	374.34	1.1533
11	30	Unbiased-30krad	368.18	369.29	1.1102
12	30	Unbiased-30krad	372.23	373.3	1.0716
13	30	Unbiased-30krad	366.57	367.4	0.8367
14	30	Unbiased-30krad	371.96	372.65	0.6907
15	30	Unbiased-30krad	373.95	374.77	0.823
16	35	Biased-30krad	372.92	373.83	0.9134
17	35	Biased-30krad	369.82	370.49	0.6722
18	35	Biased-30krad	372.94	373.93	0.9905
19	35	Biased-30krad	368.54	368.92	0.3839
20	35	Biased-30krad	367.16	367.86	0.6931
30	50	Unbiased-50krad	369.88	370.7	0.8262
31	50	Unbiased-50krad	366.36	367.27	0.9109
32	50	Unbiased-50krad	373.99	373.87	-0.1241
33	50	Unbiased-50krad	370.8	372.13	1.3218
34	50	Unbiased-50krad	375.55	376.68	1.1226
40	55	Biased-50krad	367.59	368.33	0.7432
41	55	Biased-50krad	369.54	370.64	1.1024
42	55	Biased-50krad	374.12	375.51	1.3862
43	55	Biased-50krad	371.59	373.56	1.9768
44	55	Biased-50krad	366.96	367.97	1.0105
45	100	Unbiased-100krad	367.59	367.94	0.3459
46	100	Unbiased-100krad	373.08	374.12	1.0459
47	100	Unbiased-100krad	368.01	368.92	0.9028
48	100	Unbiased-100krad	368.56	369.93	1.3769
49	100	Unbiased-100krad	373.66	374.66	1.0021
50	105	Biased-100krad	373.11	374.1	0.9881
51	105	Biased-100krad	366.9	367.86	0.961
52	105	Biased-100krad	370.9	372.29	1.3845
53	105	Biased-100krad	368.43	369.66	1.2314
54	105	Biased-100krad	373.29	374.43	1.1389

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	368.47	371.8	373.74	2.8965	369.51	372.75	374.41	2.8058	0.6694	0.9562	1.1533	0.25411
30	366.57	370.58	373.95	3.0764	367.4	371.48	374.77	3.0394	0.6907	0.90644	1.1102	0.1783
35	367.16	370.27	372.94	2.5984	367.86	371.01	373.93	2.7874	0.3839	0.73062	0.9905	0.23769
50	366.36	371.32	375.55	3.6057	367.27	372.13	376.68	3.5117	-0.1241	0.81148	1.3218	0.55737
55	366.96	369.96	374.12	2.9487	367.97	371.2	375.51	3.2835	0.7432	1.2438	1.9768	0.46973
100	367.59	370.18	373.66	2.9364	367.94	371.11	374.66	3.0785	0.3459	0.93472	1.3769	0.37422
105	366.9	370.53	373.29	2.8263	367.86	371.67	374.43	2.8453	0.961	1.1408	1.3845	0.17553

Device Test: 41.8 _SoftStart|Resistance/SS4/7/7///90.9/634//0///@R_SS_DISCHARGE





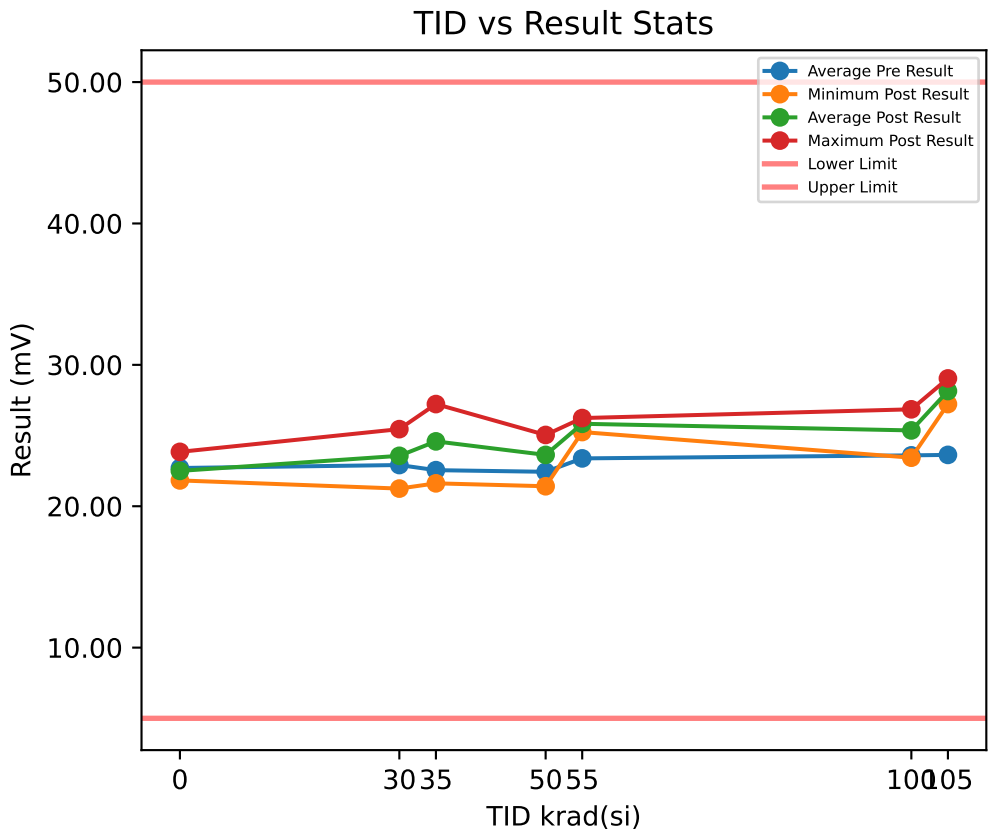
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

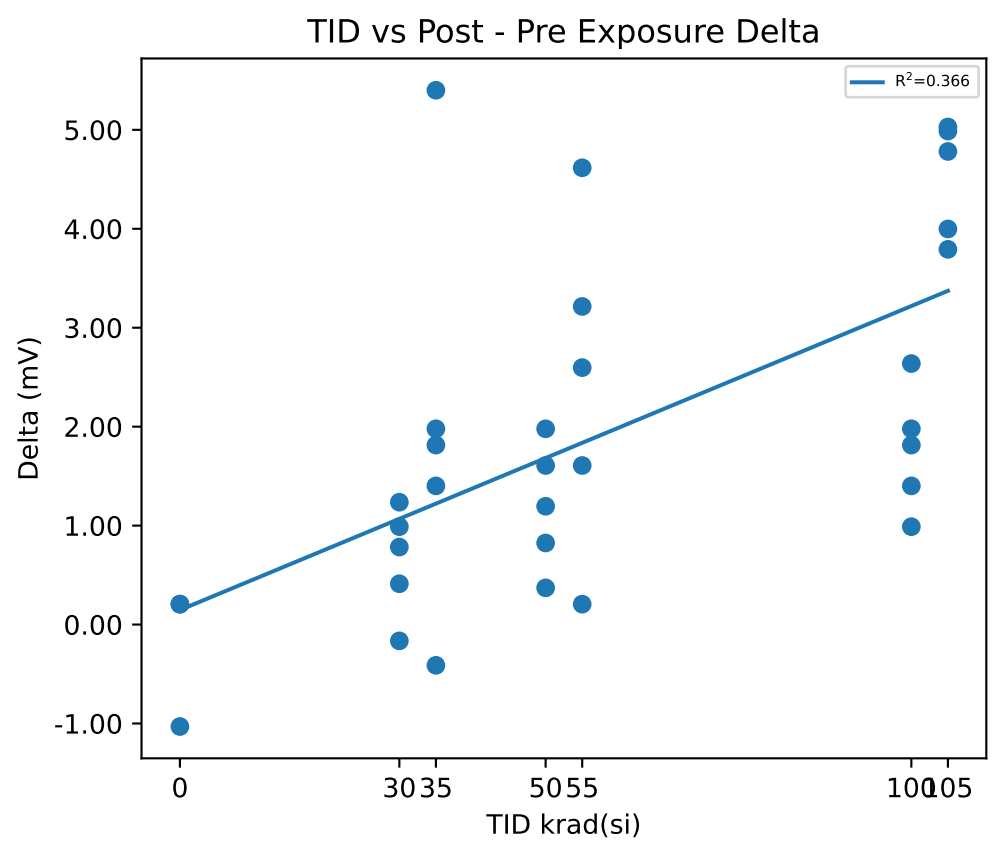
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	387.27	387.79	0.5281
2	0	CU2	382.62	383.49	0.8744
3	0	CU3	387.51	388.49	0.9849
11	30	Unbiased-30krad	382.84	383.78	0.9386
12	30	Unbiased-30krad	387.6	387.45	-0.1511
13	30	Unbiased-30krad	379.77	380.59	0.8139
14	30	Unbiased-30krad	386.66	387.39	0.7286
15	30	Unbiased-30krad	388.47	389.03	0.5526
16	35	Biased-30krad	387.54	388.23	0.6948
17	35	Biased-30krad	383.33	383.96	0.6348
18	35	Biased-30krad	387.63	388.44	0.811
19	35	Biased-30krad	380.15	381.44	1.2915
20	35	Biased-30krad	381.42	381.03	-0.3926
30	50	Unbiased-50krad	384.51	385.22	0.7091
31	50	Unbiased-50krad	379.09	379.98	0.8862
32	50	Unbiased-50krad	386.85	387.4	0.5493
33	50	Unbiased-50krad	385.3	387.83	2.5234
34	50	Unbiased-50krad	392.12	393.36	1.247
40	55	Biased-50krad	382.65	383.47	0.8263
41	55	Biased-50krad	384.45	385.3	0.8561
42	55	Biased-50krad	388.94	390.3	1.3592
43	55	Biased-50krad	387.48	388.41	0.9225
44	55	Biased-50krad	380.74	381.7	0.9629
45	100	Unbiased-100krad	381.09	382.05	0.9601
46	100	Unbiased-100krad	385.81	386.56	0.7456
47	100	Unbiased-100krad	381.49	382.38	0.8898
48	100	Unbiased-100krad	383.48	384.93	1.4514
49	100	Unbiased-100krad	387.77	388.68	0.9066
50	105	Biased-100krad	387.02	387.9	0.8819
51	105	Biased-100krad	381	382.04	1.039
52	105	Biased-100krad	385.86	387.02	1.1574
53	105	Biased-100krad	382.64	383.94	1.2946
54	105	Biased-100krad	388.43	389.69	1.2587

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	382.62	385.8	387.51	2.7552	383.49	386.59	388.49	2.7072	0.5281	0.7958	0.9849	0.23833
30	379.77	385.07	388.47	3.6598	380.59	385.65	389.03	3.4214	-0.1511	0.57652	0.9386	0.43029
35	380.15	384.01	387.63	3.4514	381.03	384.62	388.44	3.5745	-0.3926	0.6079	1.2915	0.616
50	379.09	385.58	392.12	4.6817	379.98	386.76	393.36	4.8358	0.5493	1.183	2.5234	0.79294
55	380.74	384.85	388.94	3.3758	381.7	385.84	390.3	3.5174	0.8263	0.9854	1.3592	0.21577
100	381.09	383.93	387.77	2.8522	382.05	384.92	388.68	2.8068	0.7456	0.9907	1.4514	0.26949
105	381	384.99	388.43	3.0888	382.04	386.12	389.69	3.0887	0.8819	1.1263	1.2946	0.16895

Device Test: 41.9 _SoftStart|MaxStartupVoltage/SS1/7/7///90.9/634//0///@V_SS_START





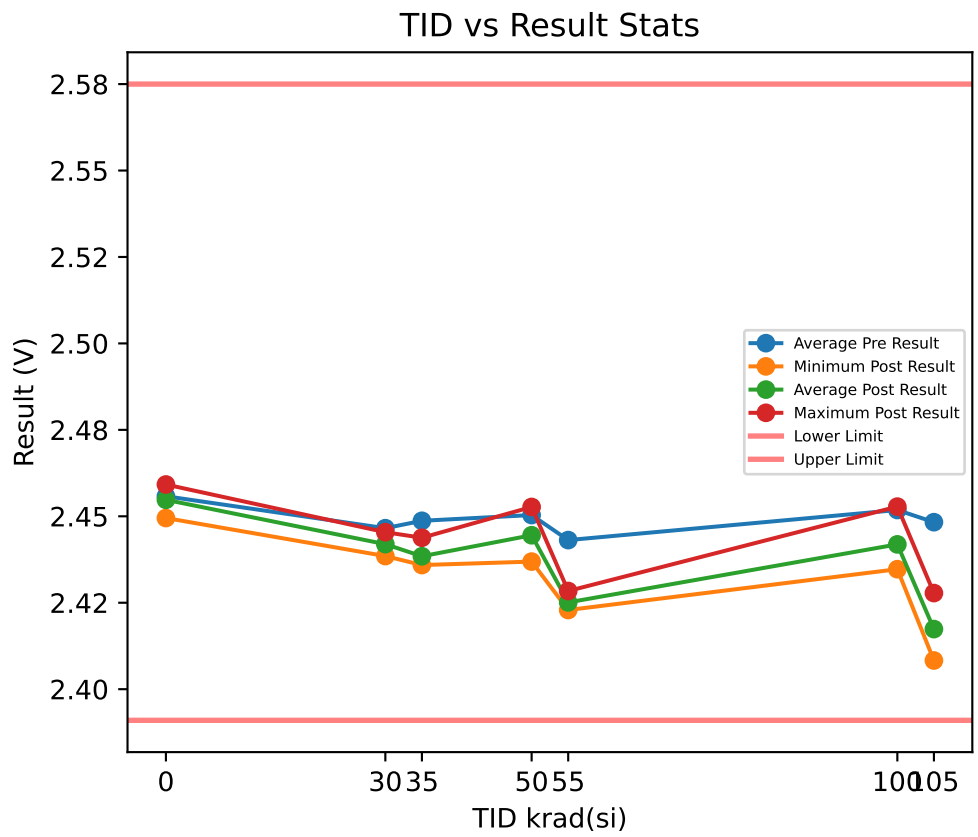
Test Results (Lower Limit = 5.0, Upper Limit = 50.0 (mV))

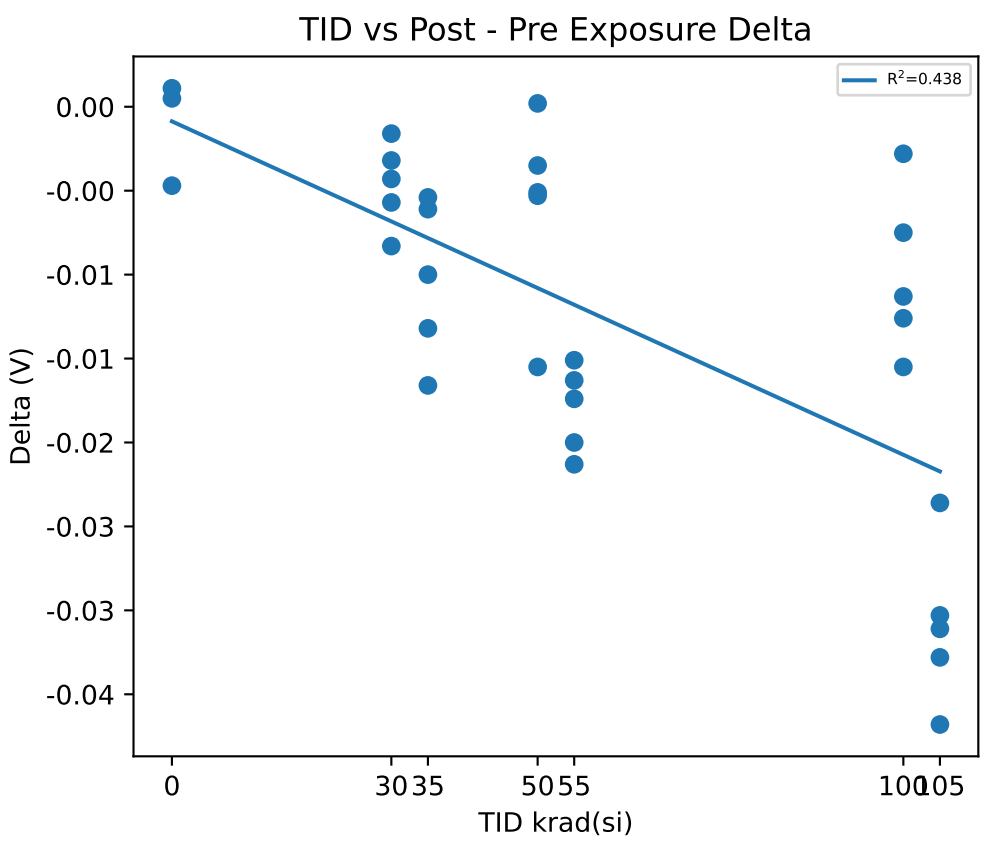
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	22.856	21.826	-1.0305
2	0	CU2	23.64	23.846	0.2061
3	0	CU3	21.62	21.826	0.2061
11	30	Unbiased-30krad	24.011	23.846	-0.1649
12	30	Unbiased-30krad	22.856	23.846	0.9893
13	30	Unbiased-30krad	20.837	21.249	0.4122
14	30	Unbiased-30krad	22.65	23.433	0.7832
15	30	Unbiased-30krad	24.217	25.453	1.2366
16	35	Biased-30krad	22.032	21.62	-0.4122
17	35	Biased-30krad	22.444	24.423	1.9786
18	35	Biased-30krad	23.433	24.835	1.4015
19	35	Biased-30krad	21.826	27.226	5.3998
20	35	Biased-30krad	23.021	24.835	1.8137
30	50	Unbiased-50krad	24.217	25.041	0.8244
31	50	Unbiased-50krad	21.249	23.227	1.9785
32	50	Unbiased-50krad	22.444	23.64	1.1954
33	50	Unbiased-50krad	21.043	21.414	0.3709
34	50	Unbiased-50krad	23.227	24.835	1.6076
40	55	Biased-50krad	21.414	26.03	4.6166
41	55	Biased-50krad	25.824	26.03	0.2061
42	55	Biased-50krad	23.021	26.236	3.2151
43	55	Biased-50krad	22.65	25.247	2.5969
44	55	Biased-50krad	24.011	25.618	1.6075
45	100	Unbiased-100krad	24.217	26.855	2.638
46	100	Unbiased-100krad	22.032	23.433	1.4015
47	100	Unbiased-100krad	25.247	26.236	0.9892
48	100	Unbiased-100krad	23.64	25.453	1.8137
49	100	Unbiased-100krad	22.856	24.835	1.9786
50	105	Biased-100krad	24.629	28.421	3.7922
51	105	Biased-100krad	23.64	27.638	3.9983
52	105	Biased-100krad	22.444	27.226	4.7815
53	105	Biased-100krad	24.011	29.039	5.0288
54	105	Biased-100krad	23.433	28.421	4.9876

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.62	22.705	23.64	1.0183	21.826	22.499	23.846	1.1661	-1.0305	-0.2061	0.2061	0.71395
30	20.837	22.914	24.217	1.3498	21.249	23.565	25.453	1.5087	-0.1649	0.65128	1.2366	0.54717
35	21.826	22.551	23.433	0.67204	21.62	24.588	27.226	1.9948	-0.4122	2.0363	5.3998	2.1074
50	21.043	22.436	24.217	1.3367	21.414	23.631	25.041	1.4592	0.3709	1.1954	1.9785	0.63257
55	21.414	23.384	25.824	1.6507	25.247	25.832	26.236	0.39684	0.2061	2.4484	4.6166	1.6618
100	22.032	23.598	25.247	1.2356	23.433	25.362	26.855	1.3227	0.9892	1.7642	2.638	0.62131
105	22.444	23.631	24.629	0.80428	27.226	28.149	29.039	0.71669	3.7922	4.5177	5.0288	0.58046

Device Test: 42.1 _THRESHOLD|RISE/PVIN1/////90.9/634//0///@UVLO_RISE_PVIN





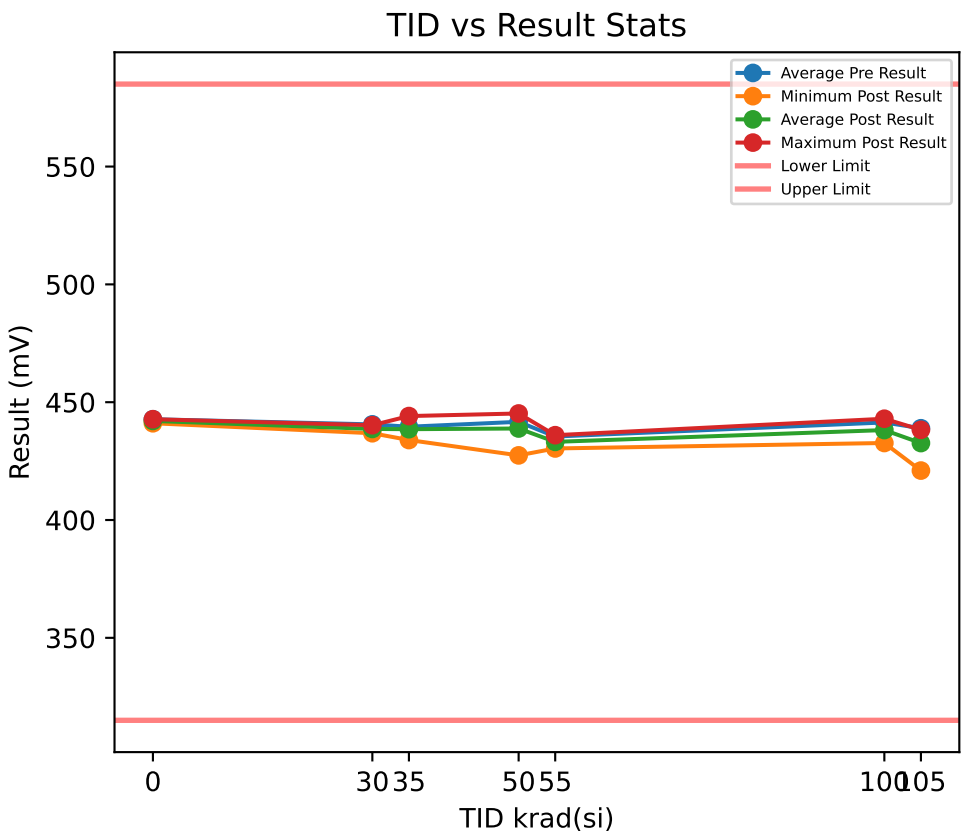
Test Results (Lower Limit = 2.391, Upper Limit = 2.575 (V))

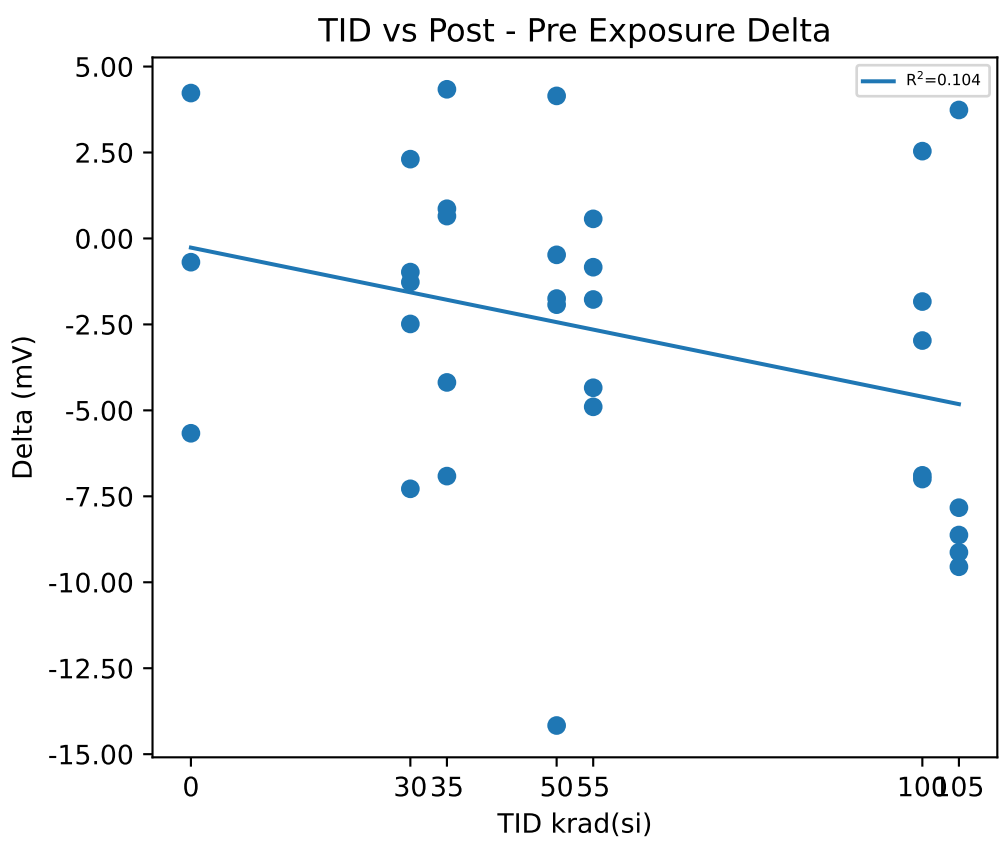
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4587	2.4592	0.0005
2	0	CU2	2.4484	2.4495	0.0011
3	0	CU3	2.4603	2.4556	-0.0047
11	30	Unbiased-30krad	2.4418	2.4402	-0.0016
12	30	Unbiased-30krad	2.4494	2.4437	-0.0057
13	30	Unbiased-30krad	2.4497	2.4454	-0.0043
14	30	Unbiased-30krad	2.4502	2.4419	-0.0083
15	30	Unbiased-30krad	2.4417	2.4385	-0.0032
16	35	Biased-30krad	2.4499	2.4438	-0.0061
17	35	Biased-30krad	2.4495	2.4363	-0.0132
18	35	Biased-30krad	2.4421	2.4367	-0.0054
19	35	Biased-30krad	2.4495	2.4395	-0.01
20	35	Biased-30krad	2.4525	2.4359	-0.0166
30	50	Unbiased-50krad	2.4546	2.4391	-0.0155
31	50	Unbiased-50krad	2.442	2.4369	-0.0051
32	50	Unbiased-50krad	2.4508	2.4455	-0.0053
33	50	Unbiased-50krad	2.4562	2.4527	-0.0035
34	50	Unbiased-50krad	2.4482	2.4484	0.0002
40	55	Biased-50krad	2.4387	2.4236	-0.0151
41	55	Biased-50krad	2.4403	2.4229	-0.0174
42	55	Biased-50krad	2.4484	2.4284	-0.02
43	55	Biased-50krad	2.4465	2.4252	-0.0213
44	55	Biased-50krad	2.4417	2.4254	-0.0163
45	100	Unbiased-100krad	2.4375	2.4347	-0.0028
46	100	Unbiased-100krad	2.4654	2.4528	-0.0126
47	100	Unbiased-100krad	2.4496	2.4383	-0.0113
48	100	Unbiased-100krad	2.4508	2.4353	-0.0155
49	100	Unbiased-100krad	2.4558	2.4483	-0.0075
50	105	Biased-100krad	2.4394	2.4083	-0.0311
51	105	Biased-100krad	2.4514	2.4278	-0.0236
52	105	Biased-100krad	2.4515	2.4187	-0.0328
53	105	Biased-100krad	2.4495	2.4127	-0.0368
54	105	Biased-100krad	2.4497	2.4194	-0.0303

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4484	2.4558	2.4603	0.0064583	2.4495	2.4548	2.4592	0.0049034	-0.0047	-0.0010333	0.0011	0.0031896
30	2.4417	2.4466	2.4502	0.0044003	2.4385	2.4419	2.4454	0.0027355	-0.0083	-0.00462	-0.0016	0.002547
35	2.4421	2.4487	2.4525	0.0038962	2.4359	2.4384	2.4438	0.0033133	-0.0166	-0.01026	-0.0054	0.004739
50	2.442	2.4504	2.4562	0.005631	2.4369	2.4445	2.4527	0.0065263	-0.0155	-0.00584	0.0002	0.0058334
55	2.4387	2.4431	2.4484	0.0041475	2.4229	2.4251	2.4284	0.002126	-0.0213	-0.01802	-0.0151	0.0025762
100	2.4375	2.4518	2.4654	0.01014	2.4347	2.4419	2.4528	0.0081873	-0.0155	-0.00994	-0.0028	0.0049186
105	2.4394	2.4483	2.4515	0.0050611	2.4083	2.4174	2.4278	0.0073951	-0.0368	-0.03092	-0.0236	0.0047986

Device Test: 42.10 _THRESHOLD|HYST/PVIN2/////90.9/634//0///@UVLO_HYST_PVIN





Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

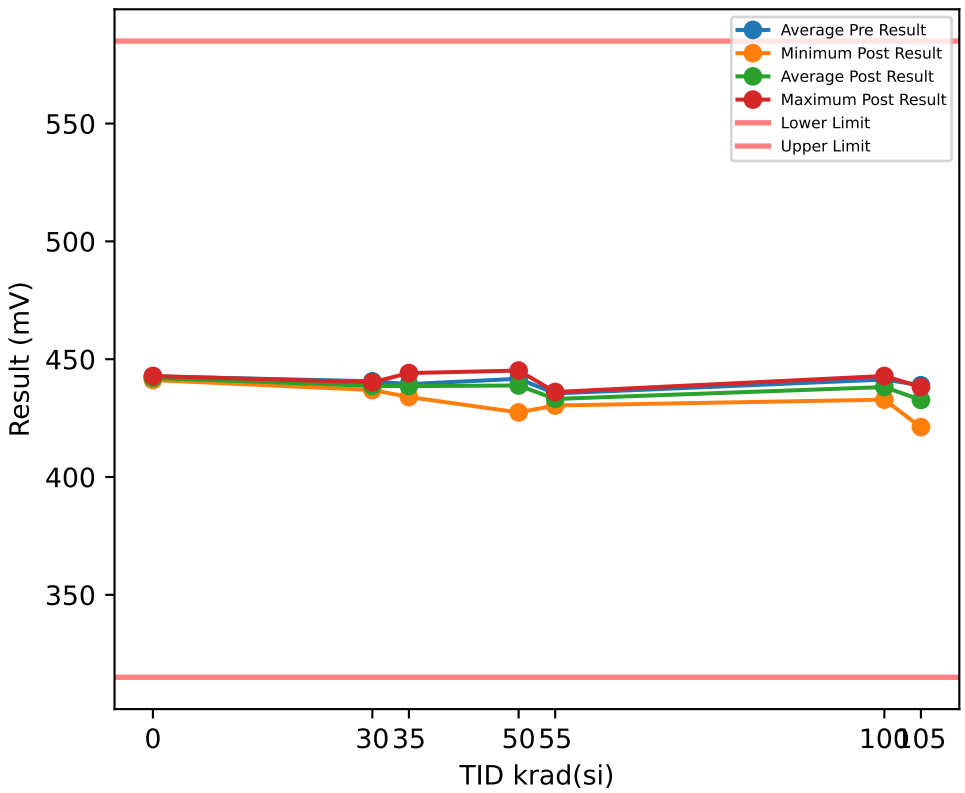
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	443.01	442.32	-0.6902
2	0	CU2	438.55	442.78	4.2291
3	0	CU3	446.73	441.06	-5.6664
11	30	Unbiased-30krad	442.33	439.84	-2.4863
12	30	Unbiased-30krad	439.8	438.82	-0.9782
13	30	Unbiased-30krad	441.5	440.23	-1.2712
14	30	Unbiased-30krad	444.11	436.83	-7.2818
15	30	Unbiased-30krad	435.22	437.53	2.3069
16	35	Biased-30krad	439.78	444.11	4.3388
17	35	Biased-30krad	444.51	437.6	-6.9123
18	35	Biased-30krad	439.96	440.83	0.8643
19	35	Biased-30krad	433.29	433.94	0.6503
20	35	Biased-30krad	440.43	436.24	-4.1872
30	50	Unbiased-50krad	441.6	427.43	-14.166
31	50	Unbiased-50krad	441.47	441	-0.4764
32	50	Unbiased-50krad	437.62	435.69	-1.9259
33	50	Unbiased-50krad	446.96	445.21	-1.7479
34	50	Unbiased-50krad	440.71	444.86	4.1465
40	55	Biased-50krad	434.04	434.61	0.5702
41	55	Biased-50krad	432.14	430.37	-1.7752
42	55	Biased-50krad	436.34	432	-4.3424
43	55	Biased-50krad	437.77	432.87	-4.8968
44	55	Biased-50krad	436.83	436	-0.8363
45	100	Unbiased-100krad	431.85	434.39	2.5397
46	100	Unbiased-100krad	449.98	442.98	-6.9978
47	100	Unbiased-100krad	440.81	438.98	-1.8352
48	100	Unbiased-100krad	439.58	432.69	-6.8897
49	100	Unbiased-100krad	444.81	441.84	-2.9693
50	105	Biased-100krad	430.53	420.98	-9.5488
51	105	Biased-100krad	434.54	438.27	3.7371
52	105	Biased-100krad	445.44	437.61	-7.831
53	105	Biased-100krad	444.15	435.52	-8.6258
54	105	Biased-100krad	440.04	430.91	-9.13

Test Statistics (mV)

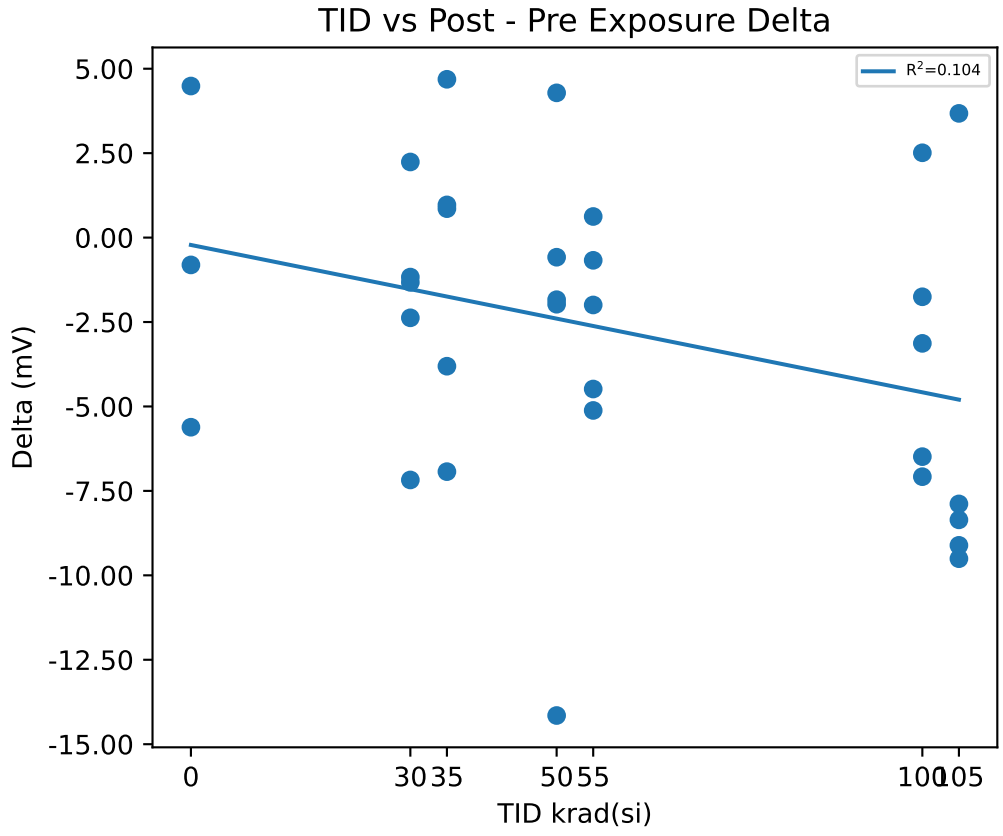
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	438.55	442.76	446.73	4.0938	441.06	442.05	442.78	0.88999	-5.6664	-0.70917	4.2291	4.9478
30	435.22	440.59	444.11	3.3786	436.83	438.65	440.23	1.4602	-7.2818	-1.9421	2.3069	3.4728
35	433.29	439.59	444.51	4.0235	433.94	438.54	444.11	3.9885	-6.9123	-1.0492	4.3388	4.4666
50	437.62	441.67	446.96	3.3674	427.43	438.84	445.21	7.4414	-14.166	-2.834	4.1465	6.7954
55	432.14	435.43	437.77	2.2929	430.37	433.17	436	2.1993	-4.8968	-2.2561	0.5702	2.3217
100	431.85	441.4	449.98	6.7114	432.69	438.17	442.98	4.5183	-6.9978	-3.2305	2.5397	3.9652
105	430.53	438.94	445.44	6.3382	420.98	432.66	438.27	7.1351	-9.5488	-6.2797	3.7371	5.636

Device Test: 42.11 _THRESHOLD|HYST/PVIN3/////90.9/634//0///@UVLO_HYST_PVIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

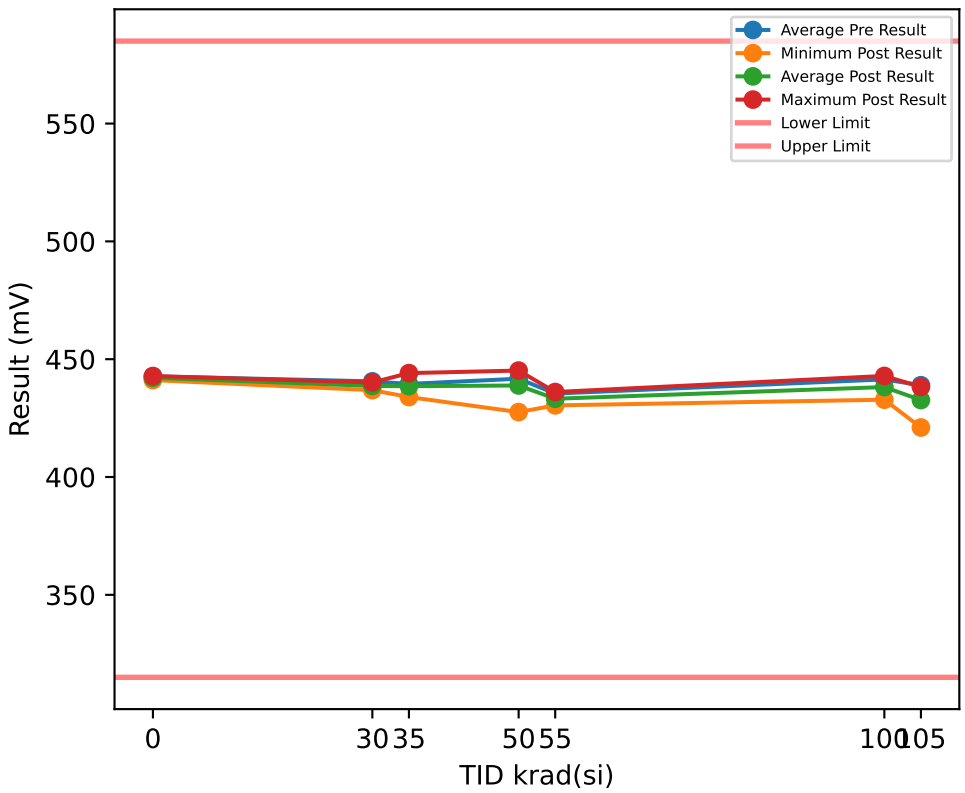
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	443.03	442.22	-0.809
2	0	CU2	438.39	442.88	4.4877
3	0	CU3	446.76	441.15	-5.6145
11	30	Unbiased-30krad	442.26	439.89	-2.3752
12	30	Unbiased-30krad	439.98	438.81	-1.1691
13	30	Unbiased-30krad	441.51	440.18	-1.3253
14	30	Unbiased-30krad	444.1	436.93	-7.1759
15	30	Unbiased-30krad	435.27	437.51	2.2389
16	35	Biased-30krad	439.42	444.11	4.6872
17	35	Biased-30krad	444.48	437.55	-6.9299
18	35	Biased-30krad	439.93	440.9	0.9681
19	35	Biased-30krad	433.08	433.94	0.8568
20	35	Biased-30krad	440.22	436.41	-3.8082
30	50	Unbiased-50krad	441.57	427.42	-14.15
31	50	Unbiased-50krad	441.53	440.95	-0.5811
32	50	Unbiased-50krad	437.77	435.8	-1.9728
33	50	Unbiased-50krad	447.03	445.19	-1.8387
34	50	Unbiased-50krad	440.57	444.86	4.2857
40	55	Biased-50krad	433.89	434.51	0.6247
41	55	Biased-50krad	432.34	430.35	-1.9948
42	55	Biased-50krad	436.38	431.9	-4.4834
43	55	Biased-50krad	437.95	432.83	-5.1179
44	55	Biased-50krad	436.75	436.08	-0.6728
45	100	Unbiased-100krad	431.95	434.46	2.5113
46	100	Unbiased-100krad	449.96	442.88	-7.0788
47	100	Unbiased-100krad	440.77	439.02	-1.7522
48	100	Unbiased-100krad	439.32	432.83	-6.4857
49	100	Unbiased-100krad	444.86	441.73	-3.1317
50	105	Biased-100krad	430.69	421.19	-9.5073
51	105	Biased-100krad	434.51	438.18	3.6777
52	105	Biased-100krad	445.49	437.6	-7.8857
53	105	Biased-100krad	443.9	435.55	-8.357
54	105	Biased-100krad	440.15	431.03	-9.1119

Test Statistics (mV)

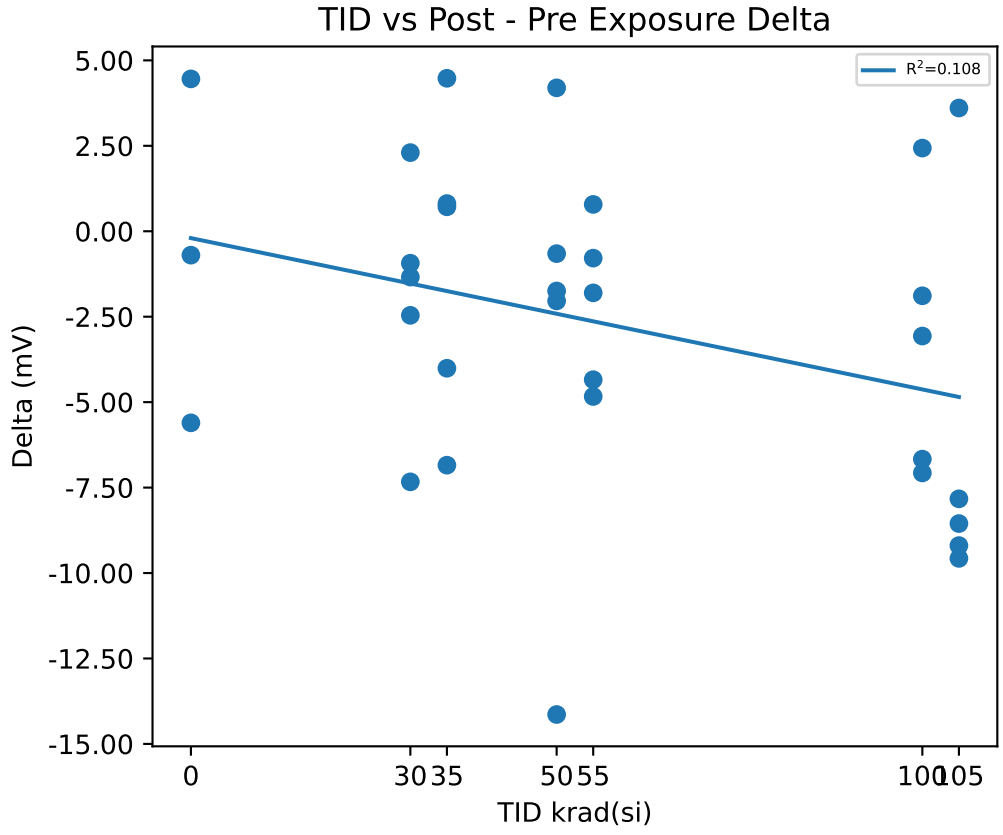
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	438.39	442.73	446.76	4.1944	441.15	442.08	442.88	0.87283	-5.6145	-0.64527	4.4877	5.0531
30	435.27	440.63	444.1	3.3395	436.93	438.66	440.18	1.4287	-7.1759	-1.9613	2.2389	3.3925
35	433.08	439.43	444.48	4.0835	433.94	438.58	444.11	3.9764	-6.9299	-0.8452	4.6872	4.5441
50	437.77	441.69	447.03	3.359	427.42	438.84	445.19	7.4274	-14.15	-2.8515	4.2857	6.811
55	432.34	435.46	437.95	2.2869	430.35	433.13	436.08	2.2335	-5.1179	-2.3288	0.6247	2.4494
100	431.95	441.37	449.96	6.6942	432.83	438.18	442.88	4.4099	-7.0788	-3.1874	2.5113	3.891
105	430.69	438.95	445.49	6.2576	421.19	432.71	438.18	7.0272	-9.5073	-6.2368	3.6777	5.5784

Device Test: 42.12 _THRESHOLD|HYST/PVIN4/////90.9/634//0///@UVLO_HYST_PVIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

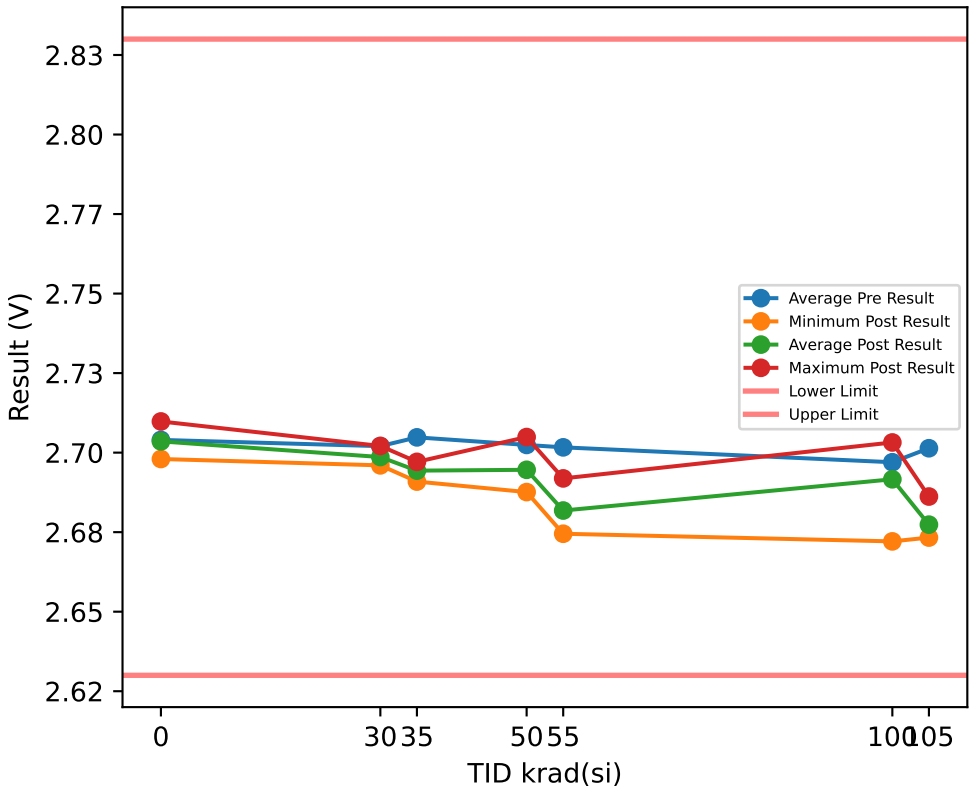
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	443.01	442.31	-0.6991
2	0	CU2	438.4	442.86	4.4577
3	0	CU3	446.73	441.12	-5.6051
11	30	Unbiased-30krad	442.35	439.89	-2.4598
12	30	Unbiased-30krad	439.77	438.83	-0.9352
13	30	Unbiased-30krad	441.45	440.11	-1.3407
14	30	Unbiased-30krad	444.19	436.86	-7.3318
15	30	Unbiased-30krad	435.25	437.55	2.3012
16	35	Biased-30krad	439.62	444.1	4.4757
17	35	Biased-30krad	444.48	437.64	-6.8441
18	35	Biased-30krad	439.94	440.75	0.8102
19	35	Biased-30krad	433.22	433.94	0.7159
20	35	Biased-30krad	440.29	436.28	-4.0084
30	50	Unbiased-50krad	441.69	427.55	-14.139
31	50	Unbiased-50krad	441.6	440.95	-0.6548
32	50	Unbiased-50krad	437.73	435.69	-2.0382
33	50	Unbiased-50krad	446.92	445.18	-1.7474
34	50	Unbiased-50krad	440.66	444.85	4.196
40	55	Biased-50krad	433.86	434.64	0.7855
41	55	Biased-50krad	432.2	430.4	-1.8026
42	55	Biased-50krad	436.36	432.01	-4.3428
43	55	Biased-50krad	437.79	432.96	-4.8344
44	55	Biased-50krad	436.86	436.07	-0.786
45	100	Unbiased-100krad	431.98	434.42	2.4338
46	100	Unbiased-100krad	449.97	442.9	-7.0714
47	100	Unbiased-100krad	440.85	438.97	-1.8881
48	100	Unbiased-100krad	439.48	432.81	-6.667
49	100	Unbiased-100krad	444.84	441.77	-3.0657
50	105	Biased-100krad	430.58	421.01	-9.5711
51	105	Biased-100krad	434.61	438.22	3.6062
52	105	Biased-100krad	445.46	437.63	-7.8286
53	105	Biased-100krad	444.05	435.5	-8.5524
54	105	Biased-100krad	440.09	430.89	-9.1967

Test Statistics (mV)

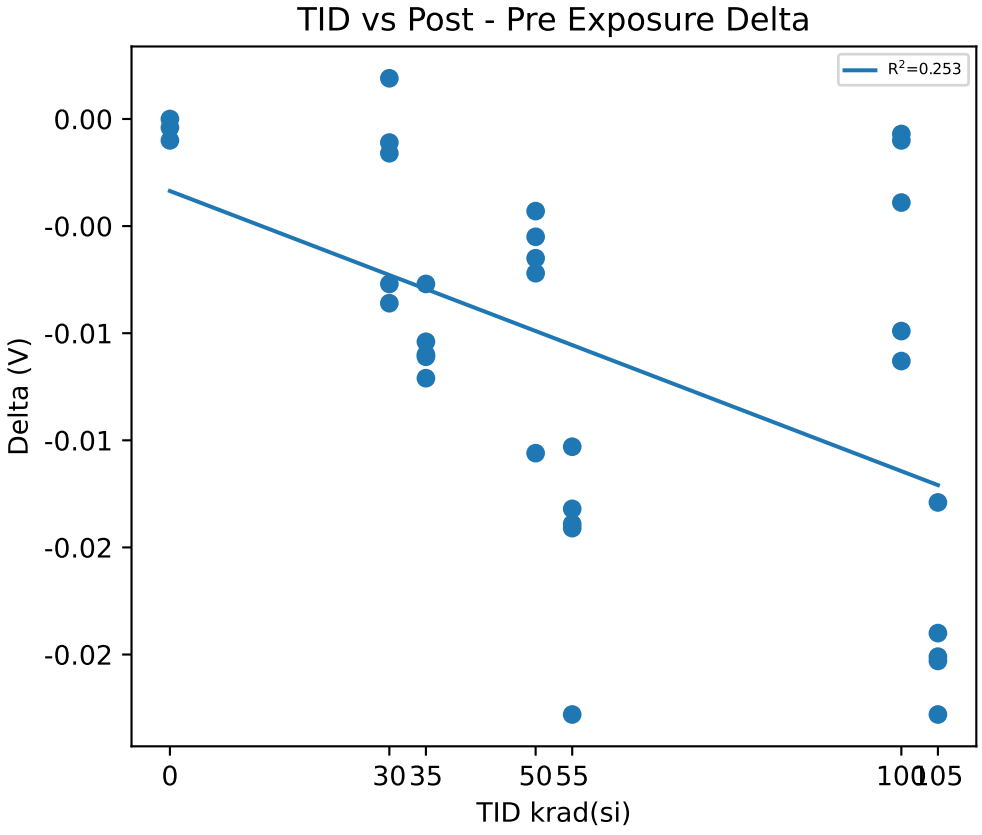
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	438.4	442.71	446.73	4.1708	441.12	442.1	442.86	0.88813	-5.6051	-0.6155	4.4577	5.0319
30	435.25	440.6	444.19	3.3919	436.86	438.65	440.11	1.4255	-7.3318	-1.9533	2.3012	3.4892
35	433.22	439.51	444.48	4.0324	433.94	438.54	444.1	3.9637	-6.8441	-0.97014	4.4757	4.4554
50	437.73	441.72	446.92	3.3234	427.55	438.84	445.18	7.3845	-14.139	-2.8767	4.196	6.7783
55	432.2	435.41	437.79	2.3102	430.4	433.22	436.07	2.2145	-4.8344	-2.1961	0.7855	2.3771
100	431.98	441.42	449.97	6.6698	432.81	438.17	442.9	4.438	-7.0714	-3.2517	2.4338	3.8882
105	430.58	438.96	445.46	6.2966	421.01	432.65	438.22	7.1158	-9.5711	-6.3085	3.6062	5.582

Device Test: 42.13 _THRESHOLD|RISE/VIN1/////90.9/634//0///@UVLO_RISE_VIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



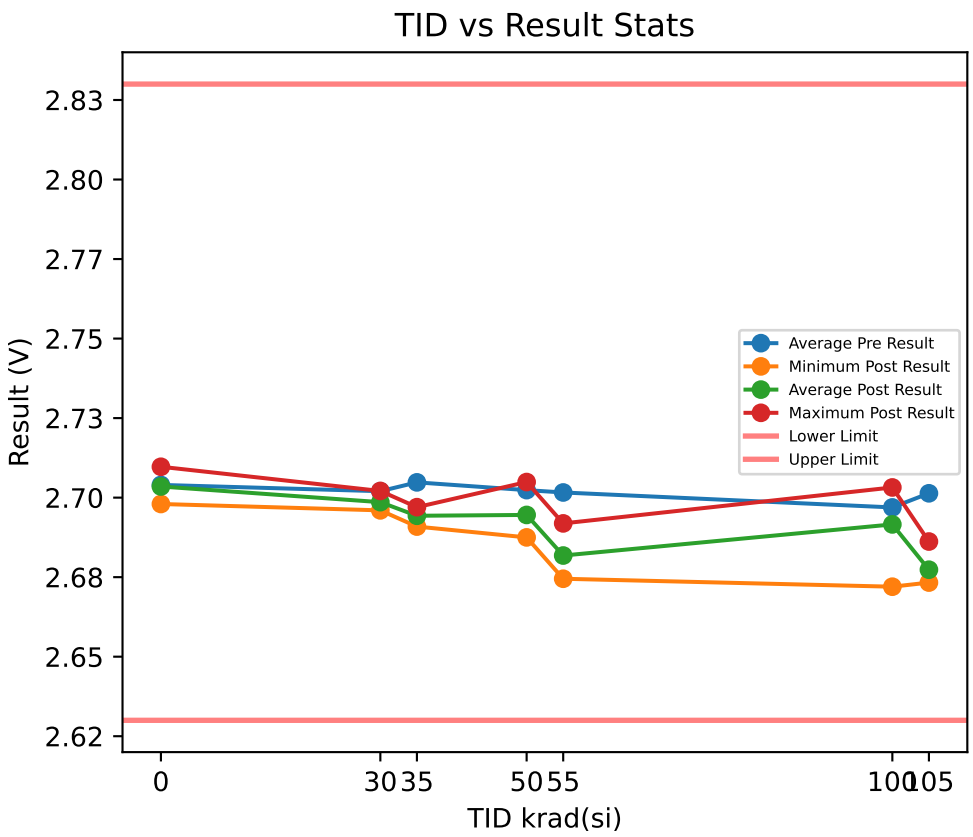
Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

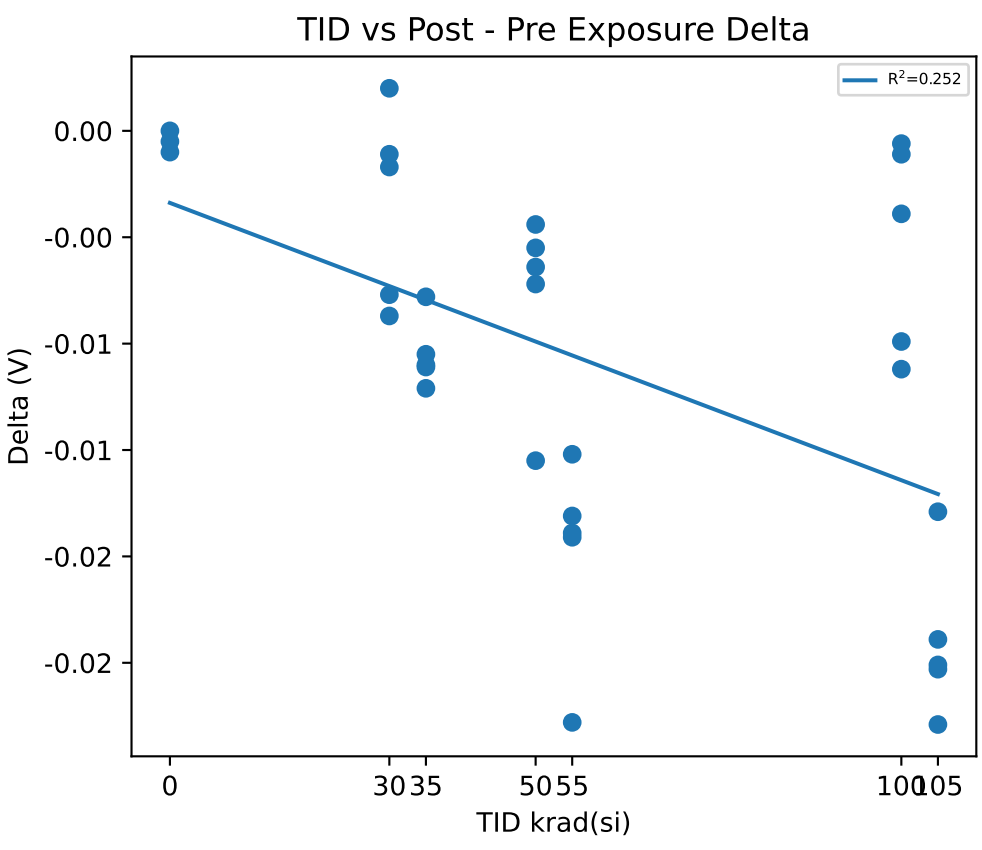
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.698	0
2	0	CU2	2.7038	2.7028	-0.001
3	0	CU3	2.7102	2.7098	-0.0004
11	30	Unbiased-30krad	2.6941	2.696	0.0019
12	30	Unbiased-30krad	2.7085	2.6999	-0.0086
13	30	Unbiased-30krad	2.7098	2.7021	-0.0077
14	30	Unbiased-30krad	2.6989	2.6973	-0.0016
15	30	Unbiased-30krad	2.6989	2.6978	-0.0011
16	35	Biased-30krad	2.7048	2.6971	-0.0077
17	35	Biased-30krad	2.7038	2.6928	-0.011
18	35	Biased-30krad	2.702	2.6909	-0.0111
19	35	Biased-30krad	2.7075	2.6971	-0.0104
20	35	Biased-30krad	2.7059	2.6938	-0.0121
30	50	Unbiased-50krad	2.7011	2.6946	-0.0065
31	50	Unbiased-50krad	2.6919	2.6876	-0.0043
32	50	Unbiased-50krad	2.7075	2.6919	-0.0156
33	50	Unbiased-50krad	2.7012	2.694	-0.0072
34	50	Unbiased-50krad	2.7104	2.7049	-0.0055
40	55	Biased-50krad	2.6932	2.6779	-0.0153
41	55	Biased-50krad	2.7023	2.6745	-0.0278
42	55	Biased-50krad	2.711	2.6919	-0.0191
43	55	Biased-50krad	2.7009	2.682	-0.0189
44	55	Biased-50krad	2.7009	2.6827	-0.0182
45	100	Unbiased-100krad	2.682	2.6721	-0.0099
46	100	Unbiased-100krad	2.7039	2.7032	-0.0007
47	100	Unbiased-100krad	2.6989	2.6979	-0.001
48	100	Unbiased-100krad	2.7032	2.6919	-0.0113
49	100	Unbiased-100krad	2.6969	2.693	-0.0039
50	105	Biased-100krad	2.7102	2.6862	-0.024
51	105	Biased-100krad	2.701	2.6759	-0.0251
52	105	Biased-100krad	2.6986	2.6733	-0.0253
53	105	Biased-100krad	2.6932	2.6753	-0.0179
54	105	Biased-100krad	2.7039	2.6761	-0.0278

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061025	2.698	2.7035	2.7098	0.0059341	-0.001	-0.00046667	0	0.00050332
30	2.6941	2.702	2.7098	0.0067954	2.696	2.6986	2.7021	0.0023994	-0.0086	-0.00342	0.0019	0.0045318
35	2.702	2.7048	2.7075	0.0020821	2.6909	2.6943	2.6971	0.0027264	-0.0121	-0.01046	-0.0077	0.0016592
50	2.6919	2.7024	2.7104	0.0071307	2.6876	2.6946	2.7049	0.0063785	-0.0156	-0.00782	-0.0043	0.0044841
55	2.6932	2.7017	2.711	0.0063319	2.6745	2.6818	2.6919	0.0065452	-0.0278	-0.01986	-0.0153	0.0046929
100	2.682	2.697	2.7039	0.0088694	2.6721	2.6916	2.7032	0.011796	-0.0113	-0.00536	-0.0007	0.0049687
105	2.6932	2.7014	2.7102	0.0063033	2.6733	2.6774	2.6862	0.0050644	-0.0278	-0.02402	-0.0179	0.0036928

Device Test: 42.14 _THRESHOLD|RISE/VIN2/////90.9/634//0///@UVLO_RISE_VIN





Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

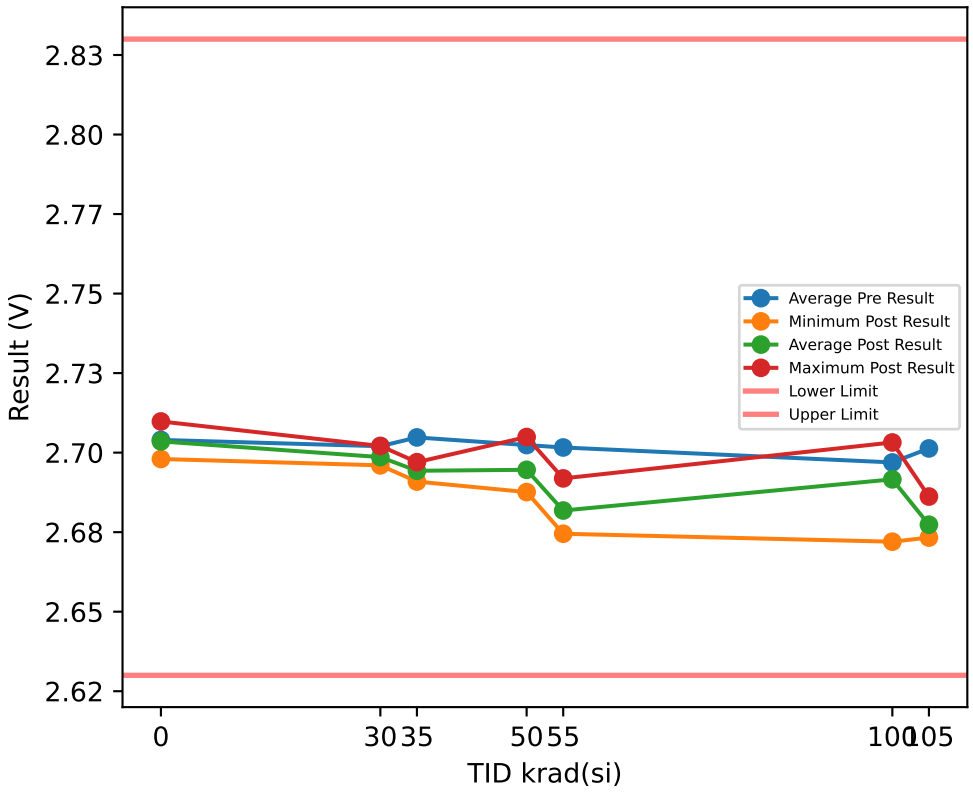
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.698	0
2	0	CU2	2.7038	2.7028	-0.001
3	0	CU3	2.7102	2.7097	-0.0005
11	30	Unbiased-30krad	2.694	2.696	0.002
12	30	Unbiased-30krad	2.7085	2.6998	-0.0087
13	30	Unbiased-30krad	2.7098	2.7021	-0.0077
14	30	Unbiased-30krad	2.6989	2.6972	-0.0017
15	30	Unbiased-30krad	2.6989	2.6978	-0.0011
16	35	Biased-30krad	2.7048	2.697	-0.0078
17	35	Biased-30krad	2.7038	2.6928	-0.011
18	35	Biased-30krad	2.702	2.6909	-0.0111
19	35	Biased-30krad	2.7075	2.697	-0.0105
20	35	Biased-30krad	2.7059	2.6938	-0.0121
30	50	Unbiased-50krad	2.701	2.6946	-0.0064
31	50	Unbiased-50krad	2.6919	2.6875	-0.0044
32	50	Unbiased-50krad	2.7074	2.6919	-0.0155
33	50	Unbiased-50krad	2.7011	2.6939	-0.0072
34	50	Unbiased-50krad	2.7104	2.7049	-0.0055
40	55	Biased-50krad	2.6931	2.6779	-0.0152
41	55	Biased-50krad	2.7023	2.6745	-0.0278
42	55	Biased-50krad	2.711	2.6919	-0.0191
43	55	Biased-50krad	2.7009	2.682	-0.0189
44	55	Biased-50krad	2.7008	2.6827	-0.0181
45	100	Unbiased-100krad	2.6819	2.672	-0.0099
46	100	Unbiased-100krad	2.7038	2.7032	-0.0006
47	100	Unbiased-100krad	2.6989	2.6978	-0.0011
48	100	Unbiased-100krad	2.7031	2.6919	-0.0112
49	100	Unbiased-100krad	2.6969	2.693	-0.0039
50	105	Biased-100krad	2.7101	2.6862	-0.0239
51	105	Biased-100krad	2.701	2.6759	-0.0251
52	105	Biased-100krad	2.6986	2.6733	-0.0253
53	105	Biased-100krad	2.6932	2.6753	-0.0179
54	105	Biased-100krad	2.7039	2.676	-0.0279

Test Statistics (V)

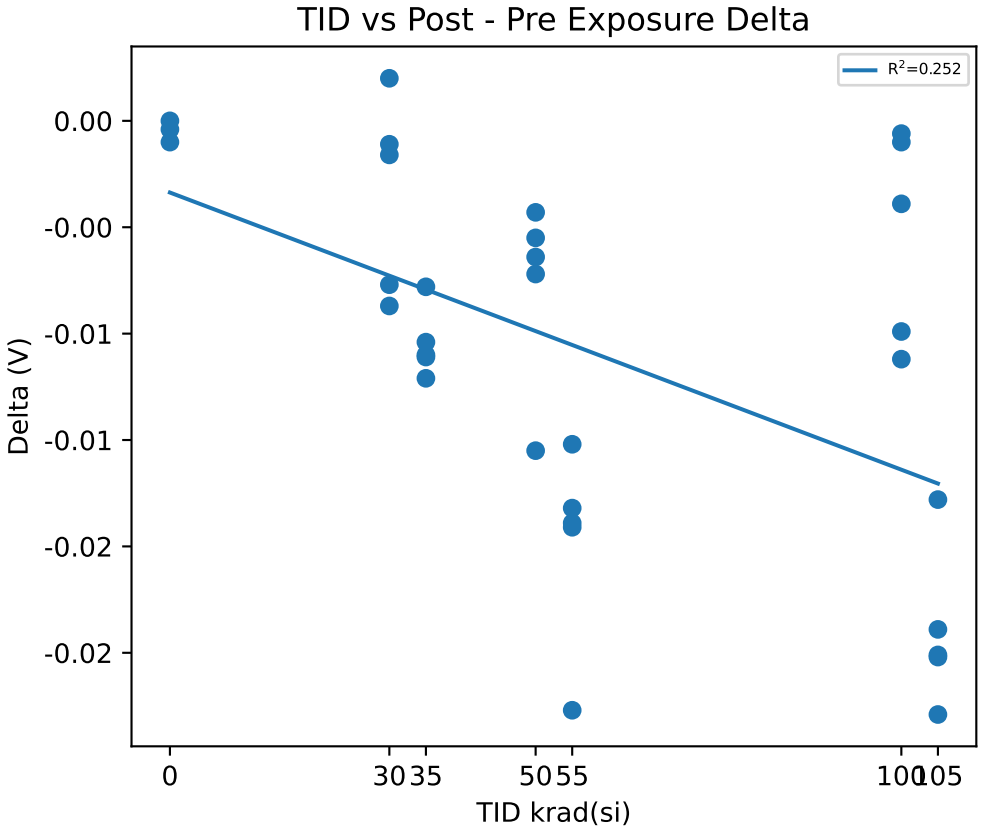
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061025	2.698	2.7035	2.7097	0.0058813	-0.001	-0.0005	0	0.0005
30	2.694	2.702	2.7098	0.0068247	2.696	2.6986	2.7021	0.0024004	-0.0087	-0.00344	0.002	0.0045802
35	2.702	2.7048	2.7075	0.0020821	2.6909	2.6943	2.697	0.0026758	-0.0121	-0.0105	-0.0078	0.0016171
50	2.6919	2.7024	2.7104	0.007122	2.6875	2.6946	2.7049	0.0064084	-0.0155	-0.0078	-0.0044	0.0044289
55	2.6931	2.7016	2.711	0.0063684	2.6745	2.6818	2.6919	0.0065452	-0.0278	-0.01982	-0.0152	0.0047262
100	2.6819	2.6969	2.7038	0.0088748	2.672	2.6916	2.7032	0.011824	-0.0112	-0.00534	-0.0006	0.004941
105	2.6932	2.7014	2.7101	0.0062684	2.6733	2.6773	2.6862	0.0050708	-0.0279	-0.02402	-0.0179	0.0037191

Device Test: 42.15 _THRESHOLD|RISE/VIN3/////90.9/634//0///@UVLO_RISE_VIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



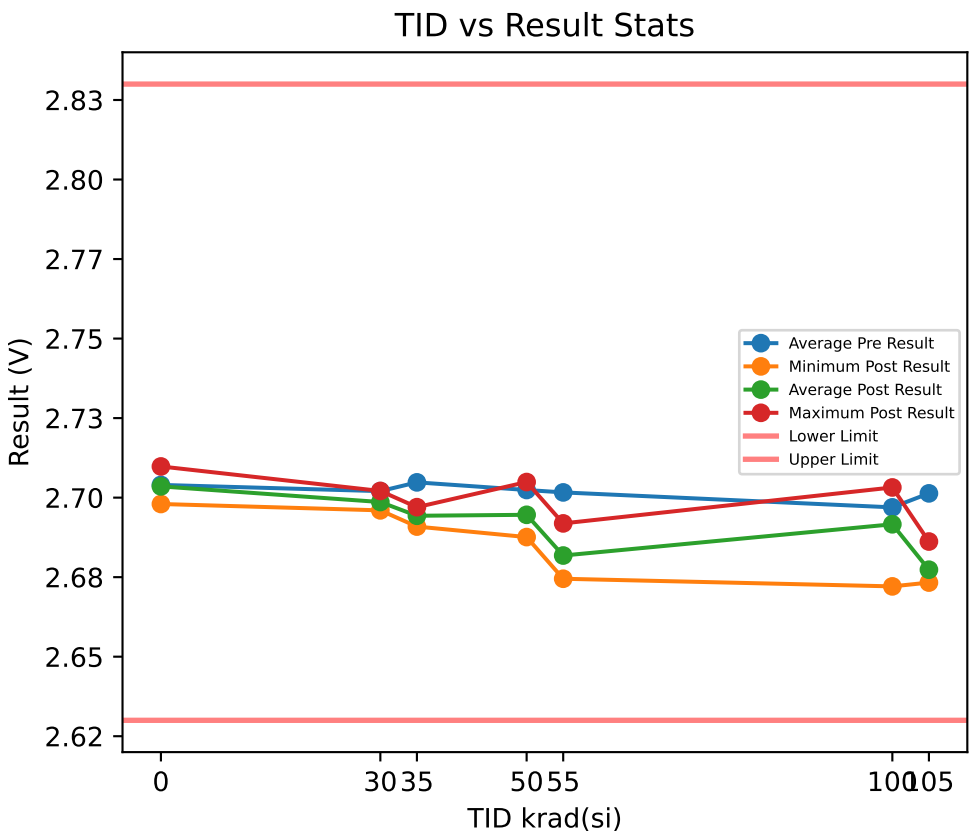
Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

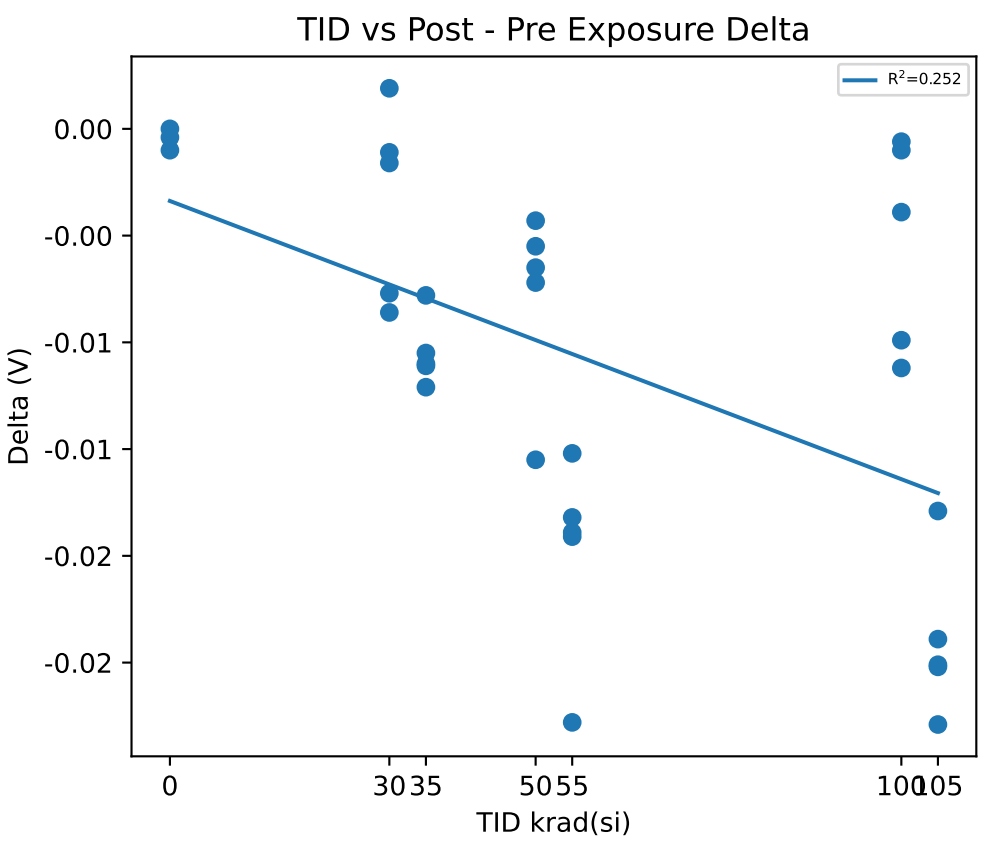
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.698	0
2	0	CU2	2.7038	2.7028	-0.001
3	0	CU3	2.7102	2.7098	-0.0004
11	30	Unbiased-30krad	2.694	2.696	0.002
12	30	Unbiased-30krad	2.7085	2.6998	-0.0087
13	30	Unbiased-30krad	2.7098	2.7021	-0.0077
14	30	Unbiased-30krad	2.6989	2.6973	-0.0016
15	30	Unbiased-30krad	2.6989	2.6978	-0.0011
16	35	Biased-30krad	2.7048	2.697	-0.0078
17	35	Biased-30krad	2.7038	2.6928	-0.011
18	35	Biased-30krad	2.702	2.6909	-0.0111
19	35	Biased-30krad	2.7074	2.697	-0.0104
20	35	Biased-30krad	2.7059	2.6938	-0.0121
30	50	Unbiased-50krad	2.701	2.6946	-0.0064
31	50	Unbiased-50krad	2.6919	2.6876	-0.0043
32	50	Unbiased-50krad	2.7074	2.6919	-0.0155
33	50	Unbiased-50krad	2.7012	2.694	-0.0072
34	50	Unbiased-50krad	2.7104	2.7049	-0.0055
40	55	Biased-50krad	2.6931	2.6779	-0.0152
41	55	Biased-50krad	2.7022	2.6745	-0.0277
42	55	Biased-50krad	2.711	2.6919	-0.0191
43	55	Biased-50krad	2.7009	2.682	-0.0189
44	55	Biased-50krad	2.7009	2.6827	-0.0182
45	100	Unbiased-100krad	2.6819	2.672	-0.0099
46	100	Unbiased-100krad	2.7038	2.7032	-0.0006
47	100	Unbiased-100krad	2.6989	2.6979	-0.001
48	100	Unbiased-100krad	2.7031	2.6919	-0.0112
49	100	Unbiased-100krad	2.6969	2.693	-0.0039
50	105	Biased-100krad	2.7101	2.6862	-0.0239
51	105	Biased-100krad	2.701	2.6759	-0.0251
52	105	Biased-100krad	2.6985	2.6733	-0.0252
53	105	Biased-100krad	2.6931	2.6753	-0.0178
54	105	Biased-100krad	2.7039	2.676	-0.0279

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061025	2.698	2.7035	2.7098	0.0059341	-0.001	-0.00046667	0	0.00050332
30	2.694	2.702	2.7098	0.0068247	2.696	2.6986	2.7021	0.0023864	-0.0087	-0.00342	0.002	0.0045899
35	2.702	2.7048	2.7074	0.0020499	2.6909	2.6943	2.697	0.0026758	-0.0121	-0.01048	-0.0078	0.0016177
50	2.6919	2.7024	2.7104	0.0071177	2.6876	2.6946	2.7049	0.0063785	-0.0155	-0.00778	-0.0043	0.0044483
55	2.6931	2.7016	2.711	0.0063629	2.6745	2.6818	2.6919	0.0065452	-0.0277	-0.01982	-0.0152	0.0046751
100	2.6819	2.6969	2.7038	0.0088748	2.672	2.6916	2.7032	0.011837	-0.0112	-0.00532	-0.0006	0.0049626
105	2.6931	2.7013	2.7101	0.0063121	2.6733	2.6773	2.6862	0.0050708	-0.0279	-0.02398	-0.0178	0.0037519

Device Test: 42.16 _THRESHOLD|RISE/VIN4/////90.9/634//0///@UVLO_RISE_VIN





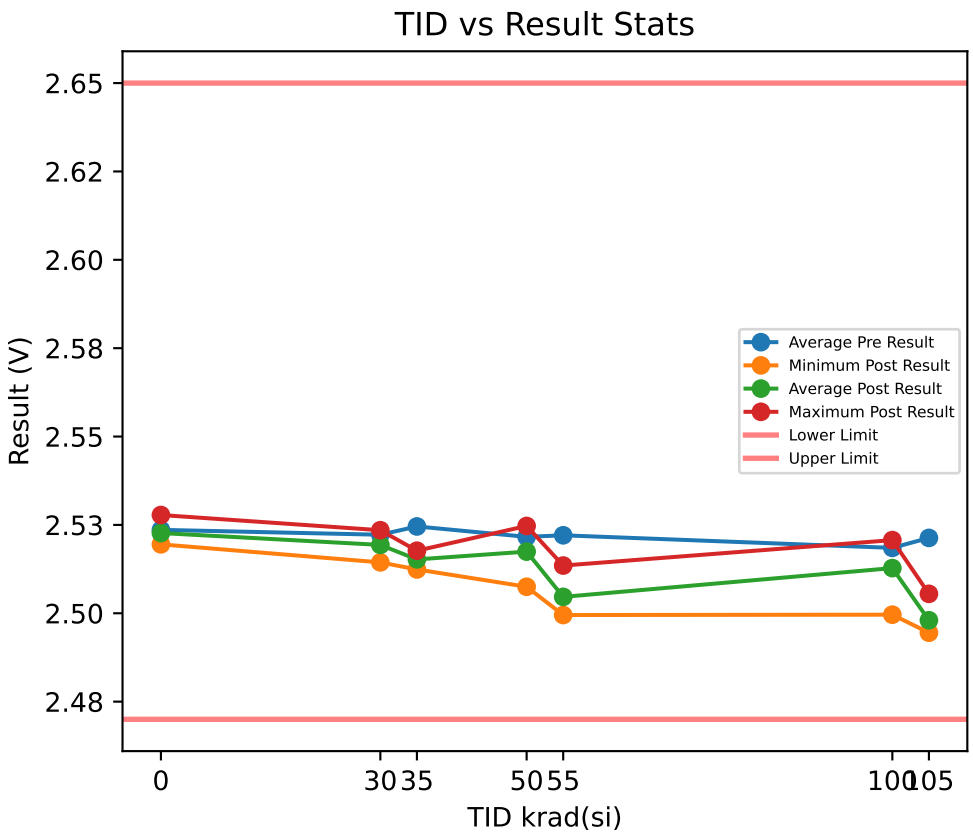
Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

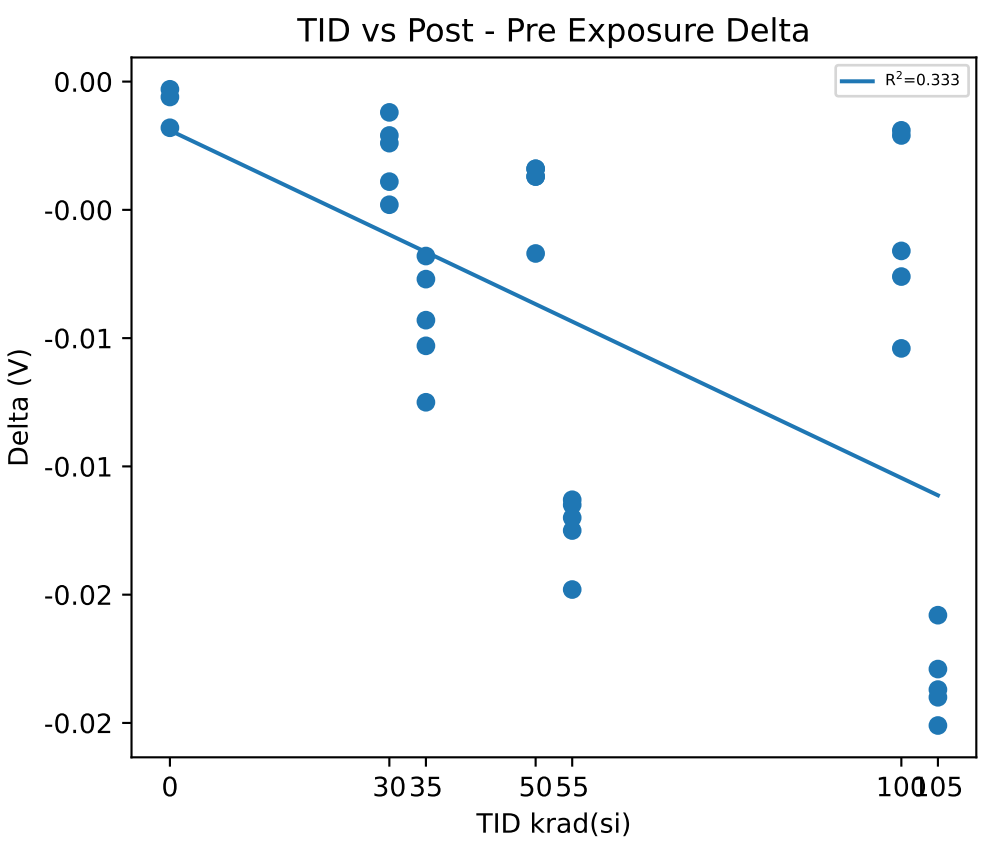
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.698	0
2	0	CU2	2.7038	2.7028	-0.001
3	0	CU3	2.7102	2.7098	-0.0004
11	30	Unbiased-30krad	2.6941	2.696	0.0019
12	30	Unbiased-30krad	2.7085	2.6999	-0.0086
13	30	Unbiased-30krad	2.7098	2.7021	-0.0077
14	30	Unbiased-30krad	2.6989	2.6973	-0.0016
15	30	Unbiased-30krad	2.6989	2.6978	-0.0011
16	35	Biased-30krad	2.7048	2.697	-0.0078
17	35	Biased-30krad	2.7038	2.6928	-0.011
18	35	Biased-30krad	2.702	2.6909	-0.0111
19	35	Biased-30krad	2.7075	2.697	-0.0105
20	35	Biased-30krad	2.7059	2.6938	-0.0121
30	50	Unbiased-50krad	2.7011	2.6946	-0.0065
31	50	Unbiased-50krad	2.6919	2.6876	-0.0043
32	50	Unbiased-50krad	2.7074	2.6919	-0.0155
33	50	Unbiased-50krad	2.7012	2.694	-0.0072
34	50	Unbiased-50krad	2.7104	2.7049	-0.0055
40	55	Biased-50krad	2.6931	2.6779	-0.0152
41	55	Biased-50krad	2.7023	2.6745	-0.0278
42	55	Biased-50krad	2.711	2.6919	-0.0191
43	55	Biased-50krad	2.7009	2.682	-0.0189
44	55	Biased-50krad	2.7009	2.6827	-0.0182
45	100	Unbiased-100krad	2.682	2.6721	-0.0099
46	100	Unbiased-100krad	2.7038	2.7032	-0.0006
47	100	Unbiased-100krad	2.6989	2.6979	-0.001
48	100	Unbiased-100krad	2.7031	2.6919	-0.0112
49	100	Unbiased-100krad	2.6969	2.693	-0.0039
50	105	Biased-100krad	2.7101	2.6862	-0.0239
51	105	Biased-100krad	2.701	2.6759	-0.0251
52	105	Biased-100krad	2.6985	2.6733	-0.0252
53	105	Biased-100krad	2.6932	2.6753	-0.0179
54	105	Biased-100krad	2.7039	2.676	-0.0279

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061025	2.698	2.7035	2.7098	0.0059341	-0.001	-0.00046667	0	0.00050332
30	2.6941	2.702	2.7098	0.0067954	2.696	2.6986	2.7021	0.0023994	-0.0086	-0.00342	0.0019	0.0045318
35	2.702	2.7048	2.7075	0.0020821	2.6909	2.6943	2.697	0.0026758	-0.0121	-0.0105	-0.0078	0.0016171
50	2.6919	2.7024	2.7104	0.007113	2.6876	2.6946	2.7049	0.0063785	-0.0155	-0.0078	-0.0043	0.0044407
55	2.6931	2.7016	2.711	0.0063654	2.6745	2.6818	2.6919	0.0065452	-0.0278	-0.01984	-0.0152	0.0047173
100	2.682	2.6969	2.7038	0.0088325	2.6721	2.6916	2.7032	0.011796	-0.0112	-0.00532	-0.0006	0.0049626
105	2.6932	2.7013	2.7101	0.0062796	2.6733	2.6773	2.6862	0.0050708	-0.0279	-0.024	-0.0179	0.0037108

Device Test: 42.17 _THRESHOLD|FALL/VIN1/////90.9/634//0///@UVLO_FALL_VIN





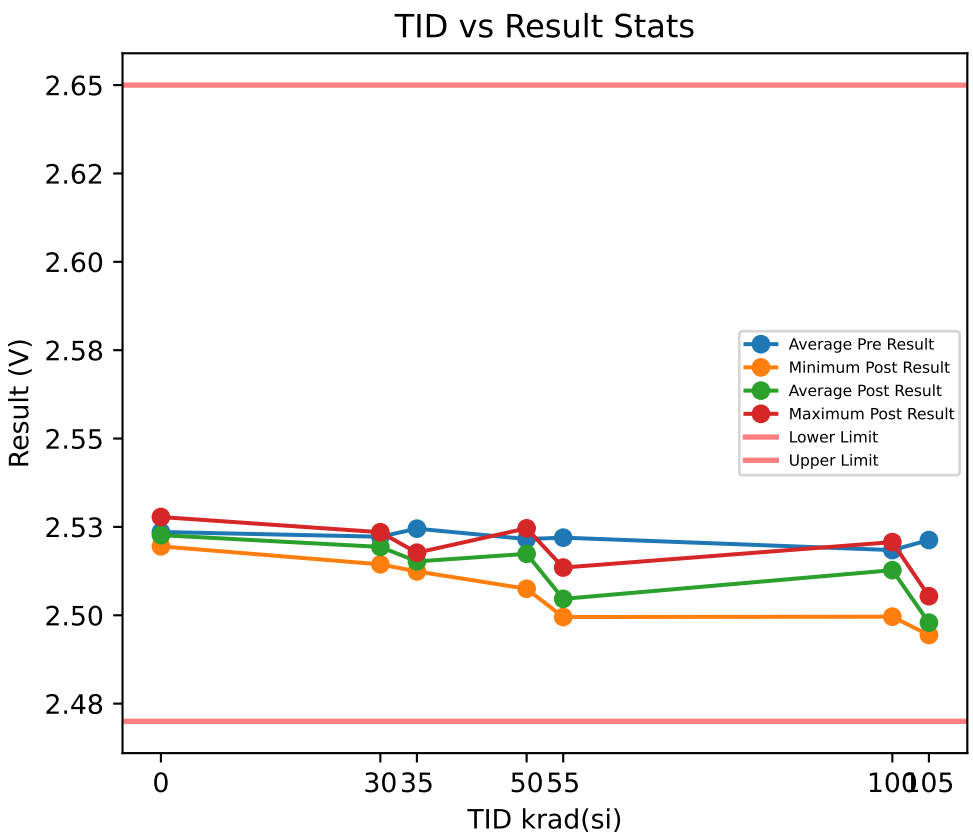
Test Results (Lower Limit = 2.47, Upper Limit = 2.65 (V))

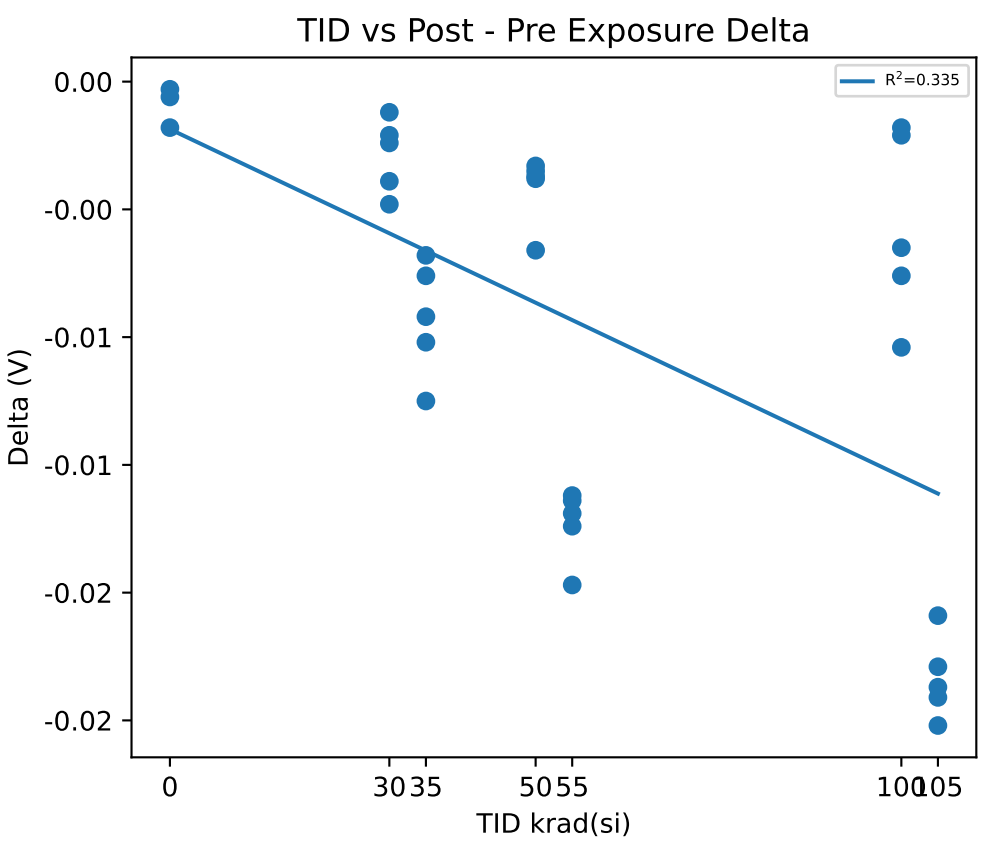
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5211	2.5208	-0.0003
2	0	CU2	2.5213	2.5195	-0.0018
3	0	CU3	2.5284	2.5278	-0.0006
11	30	Unbiased-30krad	2.5165	2.5144	-0.0021
12	30	Unbiased-30krad	2.5254	2.523	-0.0024
13	30	Unbiased-30krad	2.5283	2.5235	-0.0048
14	30	Unbiased-30krad	2.5214	2.5175	-0.0039
15	30	Unbiased-30krad	2.5195	2.5183	-0.0012
16	35	Biased-30krad	2.5245	2.5177	-0.0068
17	35	Biased-30krad	2.5201	2.5124	-0.0077
18	35	Biased-30krad	2.5249	2.5124	-0.0125
19	35	Biased-30krad	2.5277	2.5174	-0.0103
20	35	Biased-30krad	2.5256	2.5163	-0.0093
30	50	Unbiased-50krad	2.5228	2.5191	-0.0037
31	50	Unbiased-50krad	2.5109	2.5075	-0.0034
32	50	Unbiased-50krad	2.5251	2.5184	-0.0067
33	50	Unbiased-50krad	2.5209	2.5175	-0.0034
34	50	Unbiased-50krad	2.5284	2.5247	-0.0037
40	55	Biased-50krad	2.5158	2.4995	-0.0163
41	55	Biased-50krad	2.5211	2.5013	-0.0198
42	55	Biased-50krad	2.5305	2.5135	-0.017
43	55	Biased-50krad	2.524	2.5075	-0.0165
44	55	Biased-50krad	2.5189	2.5014	-0.0175
45	100	Unbiased-100krad	2.51	2.4996	-0.0104
46	100	Unbiased-100krad	2.5228	2.5207	-0.0021
47	100	Unbiased-100krad	2.5197	2.5178	-0.0019
48	100	Unbiased-100krad	2.5209	2.5143	-0.0066
49	100	Unbiased-100krad	2.5191	2.5115	-0.0076
50	105	Biased-100krad	2.5263	2.5055	-0.0208
51	105	Biased-100krad	2.5222	2.4971	-0.0251
52	105	Biased-100krad	2.5189	2.4949	-0.024
53	105	Biased-100krad	2.5174	2.4945	-0.0229
54	105	Biased-100krad	2.5218	2.4981	-0.0237

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5211	2.5236	2.5284	0.0041581	2.5195	2.5227	2.5278	0.0044643	-0.0018	-0.0009	-0.0003	0.00079373
30	2.5165	2.5222	2.5283	0.0046869	2.5144	2.5193	2.5235	0.0038591	-0.0048	-0.00288	-0.0012	0.0014481
35	2.5201	2.5246	2.5277	0.0027817	2.5124	2.5152	2.5177	0.0026444	-0.0125	-0.00932	-0.0068	0.0022387
50	2.5109	2.5216	2.5284	0.0066126	2.5075	2.5174	2.5247	0.0062288	-0.0067	-0.00418	-0.0034	0.0014167
55	2.5158	2.5221	2.5305	0.0055922	2.4995	2.5046	2.5135	0.0058041	-0.0198	-0.01742	-0.0163	0.0014096
100	2.51	2.5185	2.5228	0.0049573	2.4996	2.5128	2.5207	0.0081484	-0.0104	-0.00572	-0.0019	0.0036711
105	2.5174	2.5213	2.5263	0.0034288	2.4945	2.498	2.5055	0.0044421	-0.0251	-0.0233	-0.0208	0.0016047

Device Test: 42.18 _THRESHOLD|FALL/VIN2/////90.9/634//0///@UVLO_FALL_VIN





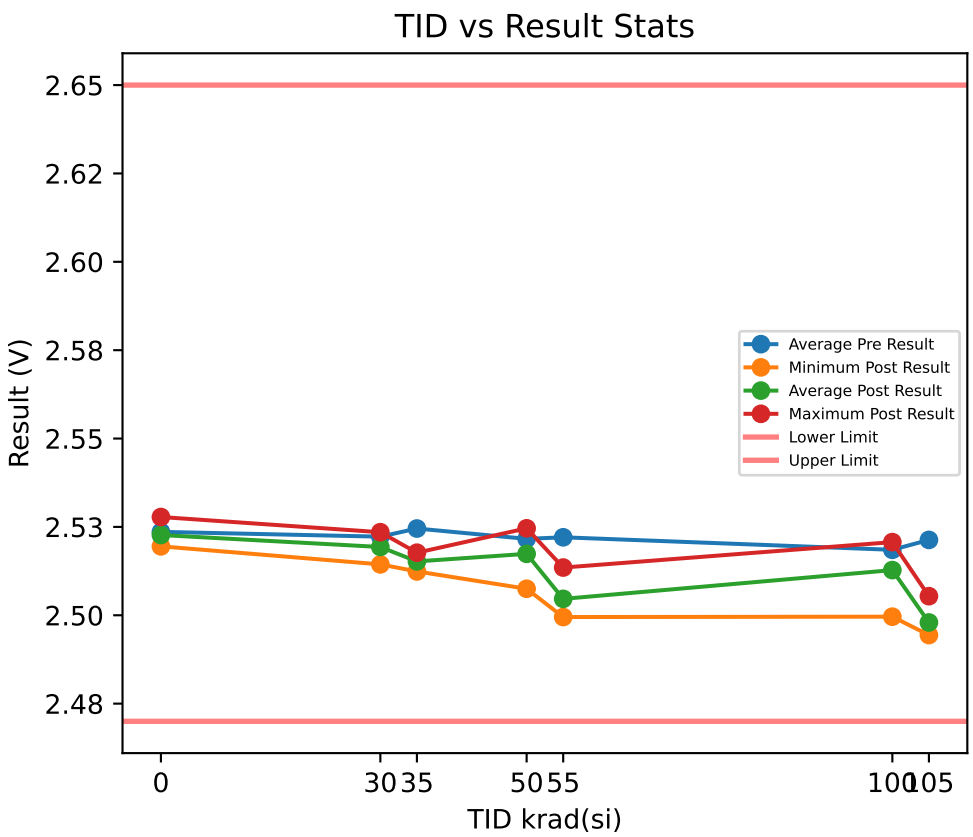
Test Results (Lower Limit = 2.47, Upper Limit = 2.65 (V))

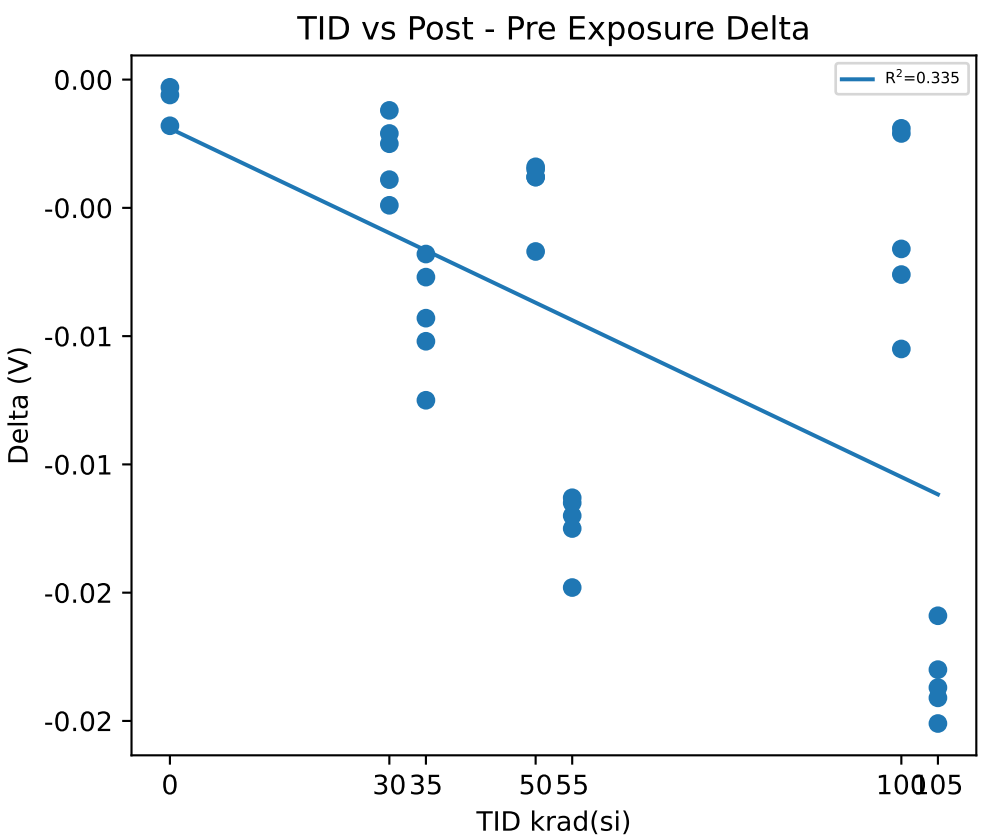
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.521	2.5207	-0.0003
2	0	CU2	2.5213	2.5195	-0.0018
3	0	CU3	2.5284	2.5278	-0.0006
11	30	Unbiased-30krad	2.5165	2.5144	-0.0021
12	30	Unbiased-30krad	2.5254	2.523	-0.0024
13	30	Unbiased-30krad	2.5283	2.5235	-0.0048
14	30	Unbiased-30krad	2.5214	2.5175	-0.0039
15	30	Unbiased-30krad	2.5195	2.5183	-0.0012
16	35	Biased-30krad	2.5245	2.5177	-0.0068
17	35	Biased-30krad	2.52	2.5124	-0.0076
18	35	Biased-30krad	2.5249	2.5124	-0.0125
19	35	Biased-30krad	2.5276	2.5174	-0.0102
20	35	Biased-30krad	2.5255	2.5163	-0.0092
30	50	Unbiased-50krad	2.5227	2.519	-0.0037
31	50	Unbiased-50krad	2.5108	2.5075	-0.0033
32	50	Unbiased-50krad	2.525	2.5184	-0.0066
33	50	Unbiased-50krad	2.5209	2.5174	-0.0035
34	50	Unbiased-50krad	2.5284	2.5246	-0.0038
40	55	Biased-50krad	2.5157	2.4995	-0.0162
41	55	Biased-50krad	2.521	2.5013	-0.0197
42	55	Biased-50krad	2.5304	2.5135	-0.0169
43	55	Biased-50krad	2.5239	2.5075	-0.0164
44	55	Biased-50krad	2.5188	2.5014	-0.0174
45	100	Unbiased-100krad	2.51	2.4996	-0.0104
46	100	Unbiased-100krad	2.5228	2.5207	-0.0021
47	100	Unbiased-100krad	2.5196	2.5178	-0.0018
48	100	Unbiased-100krad	2.5208	2.5143	-0.0065
49	100	Unbiased-100krad	2.519	2.5114	-0.0076
50	105	Biased-100krad	2.5263	2.5054	-0.0209
51	105	Biased-100krad	2.5222	2.497	-0.0252
52	105	Biased-100krad	2.5189	2.4948	-0.0241
53	105	Biased-100krad	2.5173	2.4944	-0.0229
54	105	Biased-100krad	2.5217	2.498	-0.0237

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.521	2.5236	2.5284	0.0041885	2.5195	2.5227	2.5278	0.0044859	-0.0018	-0.0009	-0.0003	0.00079373
30	2.5165	2.5222	2.5283	0.0046869	2.5144	2.5193	2.5235	0.0038591	-0.0048	-0.00288	-0.0012	0.0014481
35	2.52	2.5245	2.5276	0.0027848	2.5124	2.5152	2.5177	0.0026444	-0.0125	-0.00926	-0.0068	0.0022468
50	2.5108	2.5216	2.5284	0.0066357	2.5075	2.5174	2.5246	0.0061929	-0.0066	-0.00418	-0.0033	0.0013664
55	2.5157	2.522	2.5304	0.0055922	2.4995	2.5046	2.5135	0.0058041	-0.0197	-0.01732	-0.0162	0.0014096
100	2.51	2.5184	2.5228	0.0049364	2.4996	2.5128	2.5207	0.0081525	-0.0104	-0.00568	-0.0018	0.0036915
105	2.5173	2.5213	2.5263	0.0034543	2.4944	2.4979	2.5054	0.0044421	-0.0252	-0.02336	-0.0209	0.0016056

Device Test: 42.19 _THRESHOLD|FALL/VIN3/////90.9/634//0///@UVLO_FALL_VIN





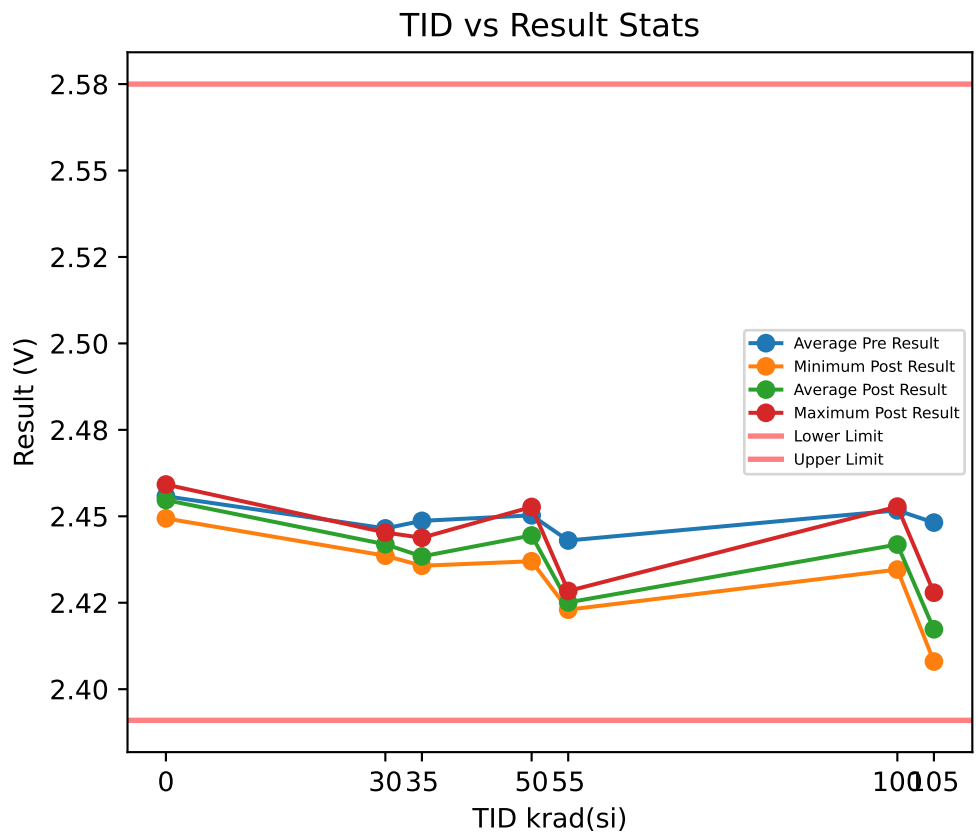
Test Results (Lower Limit = 2.47, Upper Limit = 2.65 (V))

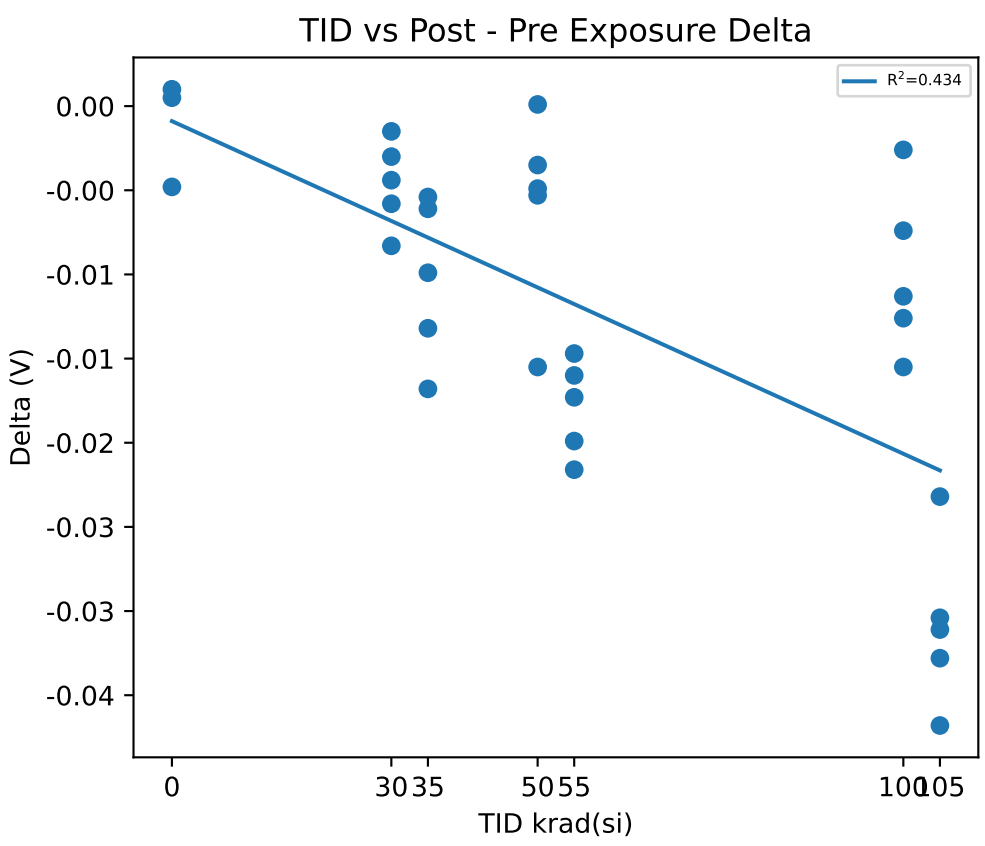
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5211	2.5208	-0.0003
2	0	CU2	2.5213	2.5195	-0.0018
3	0	CU3	2.5284	2.5278	-0.0006
11	30	Unbiased-30krad	2.5165	2.5144	-0.0021
12	30	Unbiased-30krad	2.5254	2.5229	-0.0025
13	30	Unbiased-30krad	2.5284	2.5235	-0.0049
14	30	Unbiased-30krad	2.5214	2.5175	-0.0039
15	30	Unbiased-30krad	2.5195	2.5183	-0.0012
16	35	Biased-30krad	2.5245	2.5177	-0.0068
17	35	Biased-30krad	2.5201	2.5124	-0.0077
18	35	Biased-30krad	2.5249	2.5124	-0.0125
19	35	Biased-30krad	2.5276	2.5174	-0.0102
20	35	Biased-30krad	2.5256	2.5163	-0.0093
30	50	Unbiased-50krad	2.5228	2.519	-0.0038
31	50	Unbiased-50krad	2.5109	2.5075	-0.0034
32	50	Unbiased-50krad	2.5251	2.5184	-0.0067
33	50	Unbiased-50krad	2.5209	2.5174	-0.0035
34	50	Unbiased-50krad	2.5284	2.5246	-0.0038
40	55	Biased-50krad	2.5158	2.4995	-0.0163
41	55	Biased-50krad	2.5211	2.5013	-0.0198
42	55	Biased-50krad	2.5305	2.5135	-0.017
43	55	Biased-50krad	2.524	2.5075	-0.0165
44	55	Biased-50krad	2.5189	2.5014	-0.0175
45	100	Unbiased-100krad	2.5101	2.4996	-0.0105
46	100	Unbiased-100krad	2.5228	2.5207	-0.0021
47	100	Unbiased-100krad	2.5197	2.5178	-0.0019
48	100	Unbiased-100krad	2.5209	2.5143	-0.0066
49	100	Unbiased-100krad	2.5191	2.5115	-0.0076
50	105	Biased-100krad	2.5263	2.5054	-0.0209
51	105	Biased-100krad	2.5222	2.4971	-0.0251
52	105	Biased-100krad	2.5189	2.4948	-0.0241
53	105	Biased-100krad	2.5174	2.4944	-0.023
54	105	Biased-100krad	2.5218	2.4981	-0.0237

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5211	2.5236	2.5284	0.0041581	2.5195	2.5227	2.5278	0.0044643	-0.0018	-0.0009	-0.0003	0.00079373
30	2.5165	2.5222	2.5284	0.0047194	2.5144	2.5193	2.5235	0.0038356	-0.0049	-0.00292	-0.0012	0.0014738
35	2.5201	2.5245	2.5276	0.0027537	2.5124	2.5152	2.5177	0.0026444	-0.0125	-0.0093	-0.0068	0.0022282
50	2.5109	2.5216	2.5284	0.0066126	2.5075	2.5174	2.5246	0.0061929	-0.0067	-0.00424	-0.0034	0.0013867
55	2.5158	2.5221	2.5305	0.0055922	2.4995	2.5046	2.5135	0.0058041	-0.0198	-0.01742	-0.0163	0.0014096
100	2.5101	2.5185	2.5228	0.0049145	2.4996	2.5128	2.5207	0.0081484	-0.0105	-0.00574	-0.0019	0.0037031
105	2.5174	2.5213	2.5263	0.0034288	2.4944	2.498	2.5054	0.0044377	-0.0251	-0.02336	-0.0209	0.001571

Device Test: 42.2 _THRESHOLD|RISE/PVIN2/////90.9/634//0///@UVLO_RISE_PVIN





Test Results (Lower Limit = 2.391, Upper Limit = 2.575 (V))

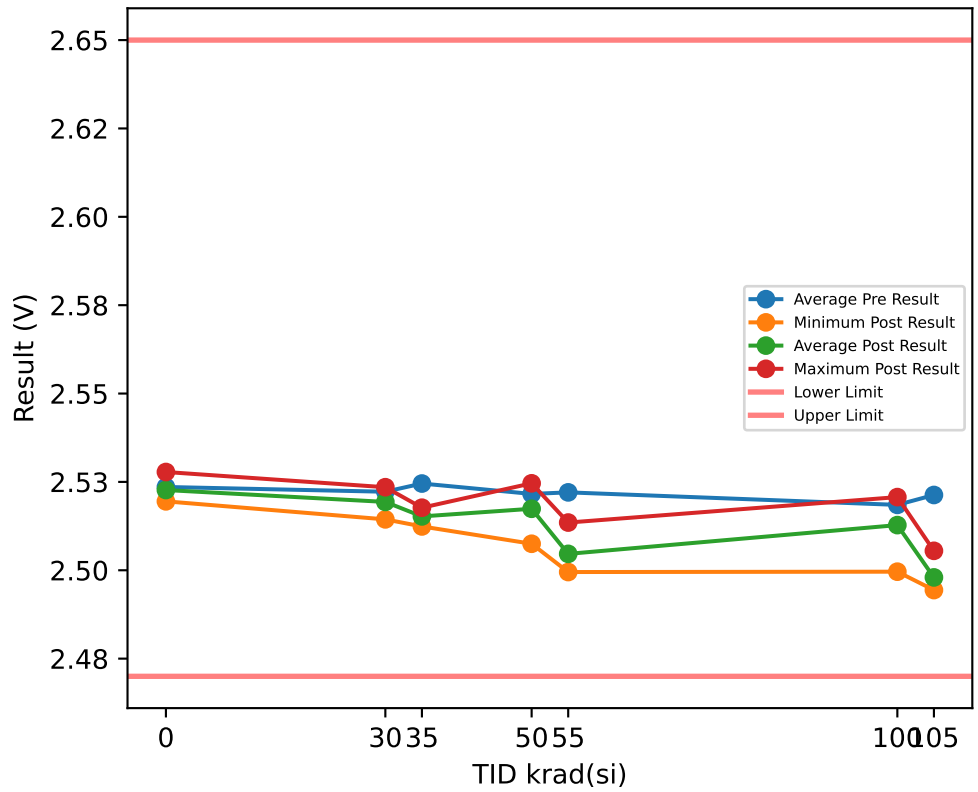
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4587	2.4592	0.0005
2	0	CU2	2.4484	2.4494	0.001
3	0	CU3	2.4603	2.4555	-0.0048
11	30	Unbiased-30krad	2.4417	2.4402	-0.0015
12	30	Unbiased-30krad	2.4495	2.4437	-0.0058
13	30	Unbiased-30krad	2.4497	2.4453	-0.0044
14	30	Unbiased-30krad	2.45	2.4417	-0.0083
15	30	Unbiased-30krad	2.4416	2.4386	-0.003
16	35	Biased-30krad	2.4499	2.4438	-0.0061
17	35	Biased-30krad	2.4495	2.4363	-0.0132
18	35	Biased-30krad	2.4421	2.4367	-0.0054
19	35	Biased-30krad	2.4494	2.4395	-0.0099
20	35	Biased-30krad	2.4525	2.4357	-0.0168
30	50	Unbiased-50krad	2.4545	2.439	-0.0155
31	50	Unbiased-50krad	2.4419	2.437	-0.0049
32	50	Unbiased-50krad	2.4506	2.4453	-0.0053
33	50	Unbiased-50krad	2.4562	2.4527	-0.0035
34	50	Unbiased-50krad	2.4482	2.4483	0.0001
40	55	Biased-50krad	2.4384	2.4237	-0.0147
41	55	Biased-50krad	2.4403	2.423	-0.0173
42	55	Biased-50krad	2.4483	2.4284	-0.0199
43	55	Biased-50krad	2.4466	2.425	-0.0216
44	55	Biased-50krad	2.4414	2.4254	-0.016
45	100	Unbiased-100krad	2.4372	2.4346	-0.0026
46	100	Unbiased-100krad	2.4654	2.4528	-0.0126
47	100	Unbiased-100krad	2.4495	2.4382	-0.0113
48	100	Unbiased-100krad	2.4507	2.4352	-0.0155
49	100	Unbiased-100krad	2.4558	2.4484	-0.0074
50	105	Biased-100krad	2.4391	2.408	-0.0311
51	105	Biased-100krad	2.4511	2.4279	-0.0232
52	105	Biased-100krad	2.4515	2.4187	-0.0328
53	105	Biased-100krad	2.4495	2.4127	-0.0368
54	105	Biased-100krad	2.4497	2.4193	-0.0304

Test Statistics (V)

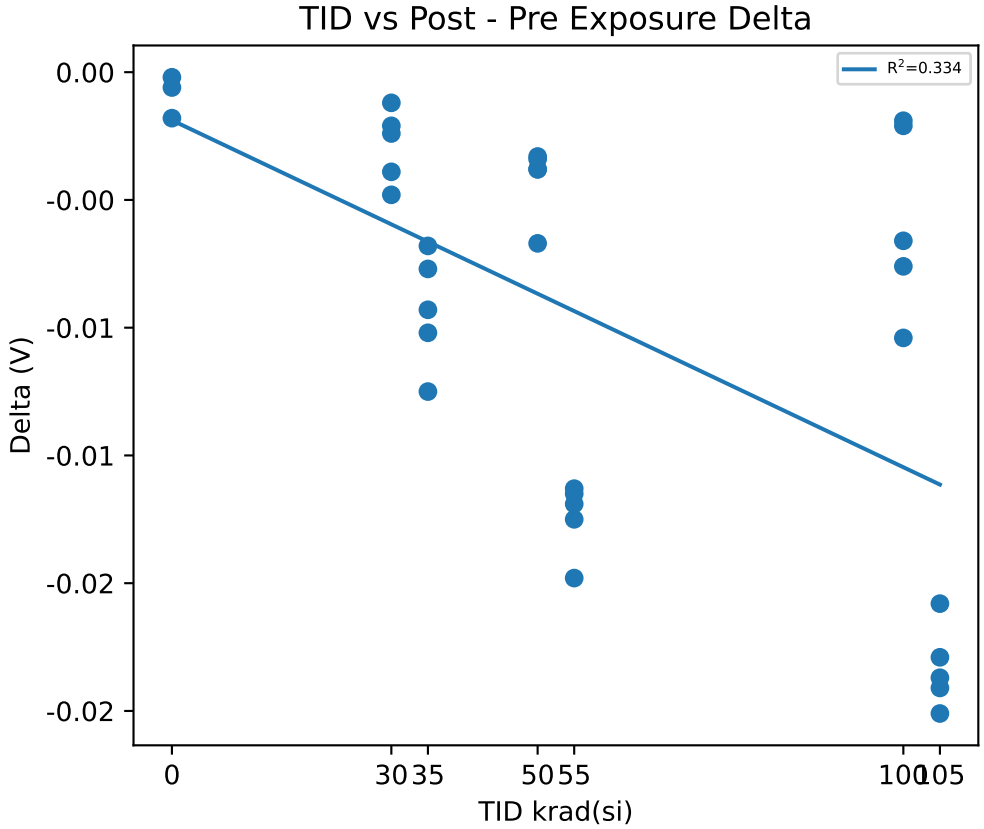
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4484	2.4558	2.4603	0.0064583	2.4494	2.4547	2.4592	0.0049487	-0.0048	-0.0011	0.001	0.003214
30	2.4416	2.4465	2.45	0.0044311	2.4386	2.4419	2.4453	0.0026749	-0.0083	-0.0046	-0.0015	0.0026144
35	2.4421	2.4487	2.4525	0.0038913	2.4357	2.4384	2.4438	0.0033526	-0.0168	-0.01028	-0.0054	0.004808
50	2.4419	2.4503	2.4562	0.005646	2.437	2.4445	2.4527	0.0064964	-0.0155	-0.00582	0.0001	0.0058148
55	2.4384	2.443	2.4483	0.0042444	2.423	2.4251	2.4284	0.0020833	-0.0216	-0.0179	-0.0147	0.002824
100	2.4372	2.4517	2.4654	0.010254	2.4346	2.4418	2.4528	0.00826	-0.0155	-0.00988	-0.0026	0.0050037
105	2.4391	2.4482	2.4515	0.005149	2.408	2.4173	2.4279	0.0075161	-0.0368	-0.03086	-0.0232	0.0049495

Device Test: 42.20 _THRESHOLD|FALL/VIN4/////90.9/634//0///@UVLO_FALL_VIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



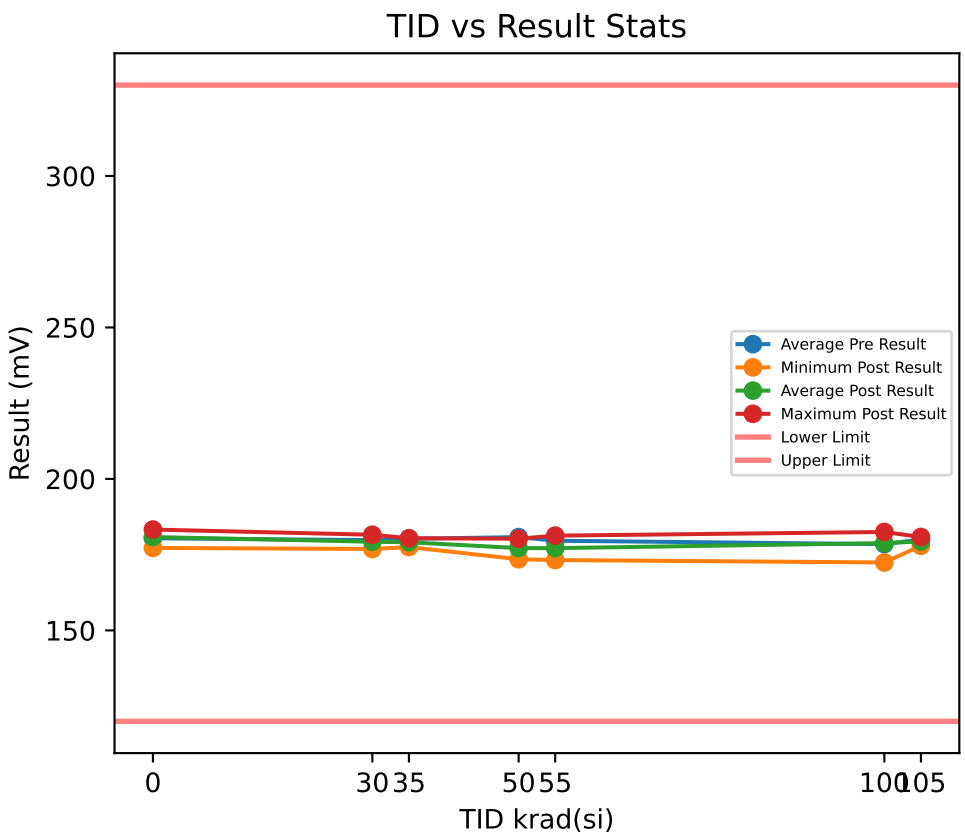
Test Results (Lower Limit = 2.47, Upper Limit = 2.65 (V))

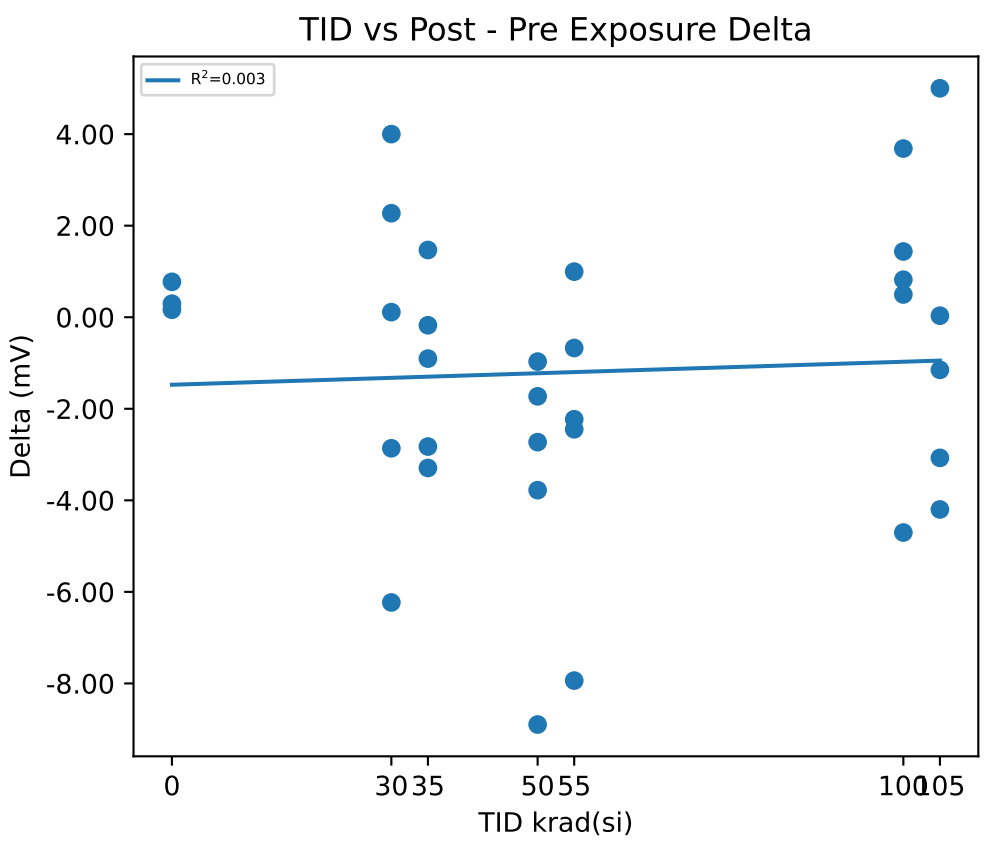
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.521	2.5208	-0.0002
2	0	CU2	2.5213	2.5195	-0.0018
3	0	CU3	2.5284	2.5278	-0.0006
11	30	Unbiased-30krad	2.5165	2.5144	-0.0021
12	30	Unbiased-30krad	2.5254	2.523	-0.0024
13	30	Unbiased-30krad	2.5283	2.5235	-0.0048
14	30	Unbiased-30krad	2.5214	2.5175	-0.0039
15	30	Unbiased-30krad	2.5195	2.5183	-0.0012
16	35	Biased-30krad	2.5245	2.5177	-0.0068
17	35	Biased-30krad	2.5201	2.5124	-0.0077
18	35	Biased-30krad	2.5249	2.5124	-0.0125
19	35	Biased-30krad	2.5276	2.5174	-0.0102
20	35	Biased-30krad	2.5256	2.5163	-0.0093
30	50	Unbiased-50krad	2.5228	2.519	-0.0038
31	50	Unbiased-50krad	2.5108	2.5075	-0.0033
32	50	Unbiased-50krad	2.5251	2.5184	-0.0067
33	50	Unbiased-50krad	2.5209	2.5175	-0.0034
34	50	Unbiased-50krad	2.5284	2.5246	-0.0038
40	55	Biased-50krad	2.5158	2.4995	-0.0163
41	55	Biased-50krad	2.5211	2.5013	-0.0198
42	55	Biased-50krad	2.5304	2.5135	-0.0169
43	55	Biased-50krad	2.524	2.5075	-0.0165
44	55	Biased-50krad	2.5189	2.5014	-0.0175
45	100	Unbiased-100krad	2.51	2.4996	-0.0104
46	100	Unbiased-100krad	2.5228	2.5207	-0.0021
47	100	Unbiased-100krad	2.5197	2.5178	-0.0019
48	100	Unbiased-100krad	2.5209	2.5143	-0.0066
49	100	Unbiased-100krad	2.5191	2.5115	-0.0076
50	105	Biased-100krad	2.5263	2.5055	-0.0208
51	105	Biased-100krad	2.5222	2.4971	-0.0251
52	105	Biased-100krad	2.5189	2.4948	-0.0241
53	105	Biased-100krad	2.5173	2.4944	-0.0229
54	105	Biased-100krad	2.5218	2.4981	-0.0237

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.521	2.5236	2.5284	0.0041885	2.5195	2.5227	2.5278	0.0044643	-0.0018	-0.00086667	-0.0002	0.00083267
30	2.5165	2.5222	2.5283	0.0046869	2.5144	2.5193	2.5235	0.0038591	-0.0048	-0.00288	-0.0012	0.0014481
35	2.5201	2.5245	2.5276	0.0027537	2.5124	2.5152	2.5177	0.0026444	-0.0125	-0.0093	-0.0068	0.0022282
50	2.5108	2.5216	2.5284	0.0066532	2.5075	2.5174	2.5246	0.0061931	-0.0067	-0.0042	-0.0033	0.001416
55	2.5158	2.522	2.5304	0.0055545	2.4995	2.5046	2.5135	0.0058041	-0.0198	-0.0174	-0.0163	0.0014177
100	2.51	2.5185	2.5228	0.0049573	2.4996	2.5128	2.5207	0.0081484	-0.0104	-0.00572	-0.0019	0.0036711
105	2.5173	2.5213	2.5263	0.0034576	2.4944	2.498	2.5055	0.0044796	-0.0251	-0.02332	-0.0208	0.0016162

Device Test: 42.21 _THRESHOLD|HYST/VIN1/////90.9/634//0///@UVLO_HYST_VIN





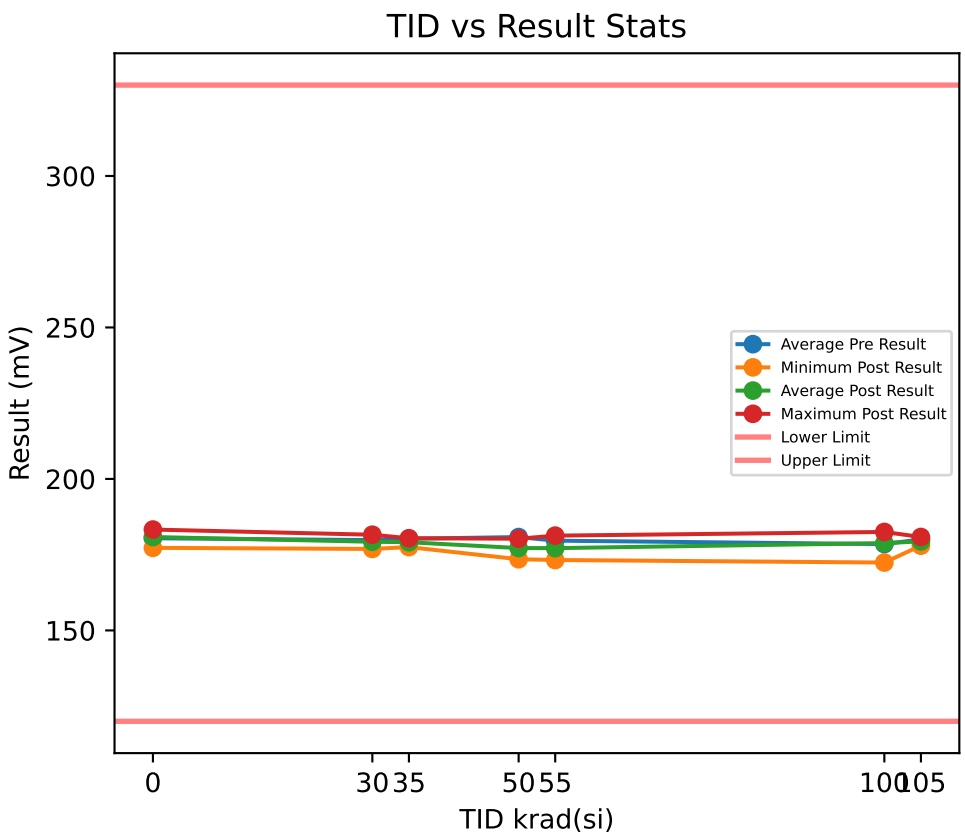
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

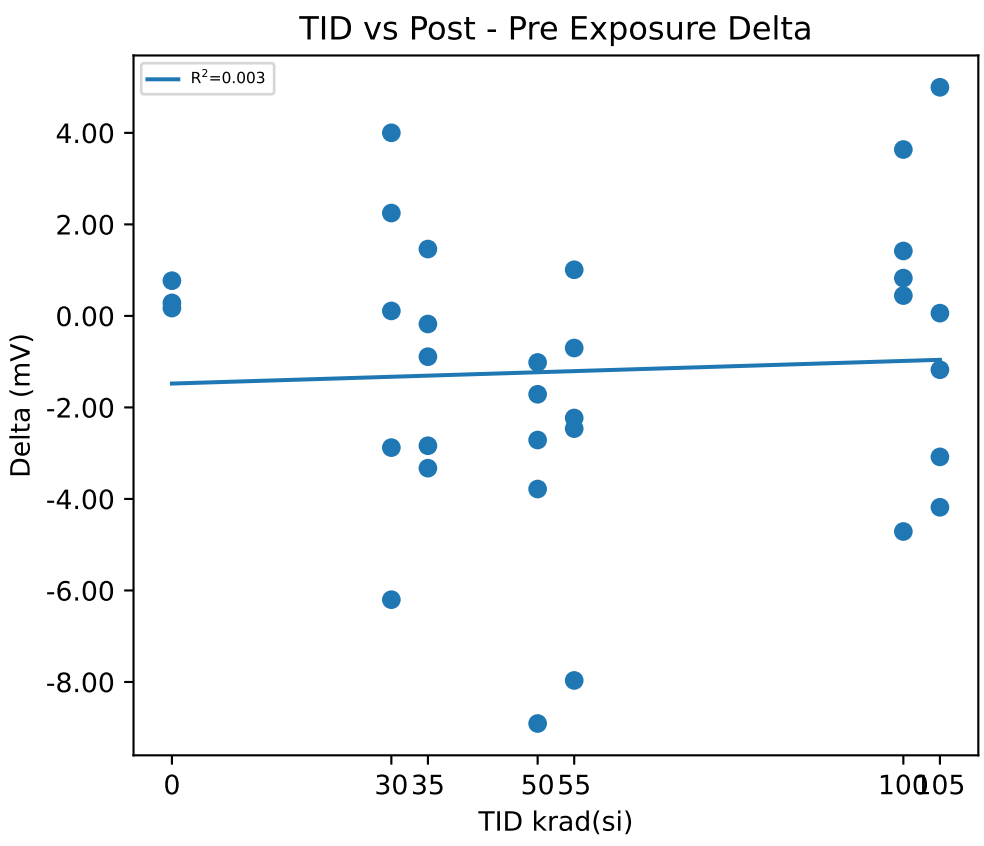
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.94	177.23	0.2955
2	0	CU2	182.52	183.29	0.7732
3	0	CU3	181.77	181.93	0.1638
11	30	Unbiased-30krad	177.58	181.58	4.0004
12	30	Unbiased-30krad	183.11	176.88	-6.2309
13	30	Unbiased-30krad	181.49	178.62	-2.8636
14	30	Unbiased-30krad	177.47	179.74	2.2724
15	30	Unbiased-30krad	179.41	179.52	0.1113
16	35	Biased-30krad	180.27	179.37	-0.9037
17	35	Biased-30krad	183.72	180.43	-3.2931
18	35	Biased-30krad	177.08	178.55	1.4684
19	35	Biased-30krad	179.82	179.64	-0.1754
20	35	Biased-30krad	180.34	177.51	-2.8253
30	50	Unbiased-50krad	178.28	175.56	-2.729
31	50	Unbiased-50krad	181.05	180.08	-0.9694
32	50	Unbiased-50krad	182.39	173.49	-8.8975
33	50	Unbiased-50krad	180.28	176.5	-3.7785
34	50	Unbiased-50krad	181.99	180.26	-1.7284
40	55	Biased-50krad	177.4	178.4	0.996
41	55	Biased-50krad	181.16	173.23	-7.938
42	55	Biased-50krad	180.59	178.36	-2.2294
43	55	Biased-50krad	176.95	174.5	-2.4481
44	55	Biased-50krad	181.96	181.28	-0.6724
45	100	Unbiased-100krad	171.93	172.43	0.4967
46	100	Unbiased-100krad	181.06	182.49	1.4358
47	100	Unbiased-100krad	179.24	180.06	0.82
48	100	Unbiased-100krad	182.28	177.57	-4.7037
49	100	Unbiased-100krad	177.86	181.55	3.6848
50	105	Biased-100krad	183.84	180.76	-3.0727
51	105	Biased-100krad	178.8	178.83	0.0334
52	105	Biased-100krad	179.62	178.47	-1.1497
53	105	Biased-100krad	175.84	180.84	5.0014
54	105	Biased-100krad	182.13	177.93	-4.1994

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.94	180.41	182.52	3.0282	177.23	180.82	183.29	3.1785	0.1638	0.41083	0.7732	0.32065
30	177.47	179.81	183.11	2.465	176.88	179.27	181.58	1.7146	-6.2309	-0.54208	4.0004	4.0846
35	177.08	180.25	183.72	2.3619	177.51	179.1	180.43	1.1137	-3.2931	-1.1458	1.4684	1.9536
50	178.28	180.8	182.39	1.6287	173.49	177.18	180.26	2.9436	-8.8975	-3.6206	-0.9694	3.1335
55	176.95	179.61	181.96	2.2813	173.23	177.15	181.28	3.2602	-7.938	-2.4584	0.996	3.3616
100	171.93	178.47	182.28	4.027	172.43	178.82	182.49	4.0262	-4.7037	0.34672	3.6848	3.0855
105	175.84	180.04	183.84	3.0888	177.93	179.37	180.84	1.3473	-4.1994	-0.6774	5.0014	3.5749

Device Test: 42.22 _THRESHOLD|HYST/VIN2/////90.9/634//0///@UVLO_HYST_VIN





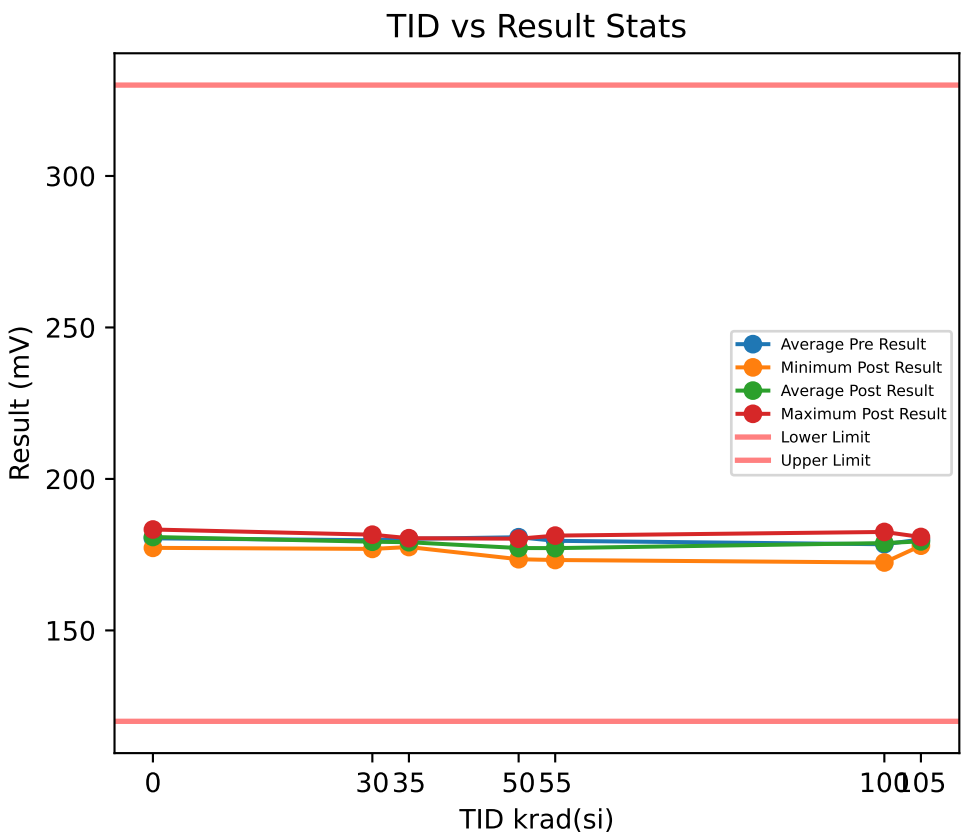
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

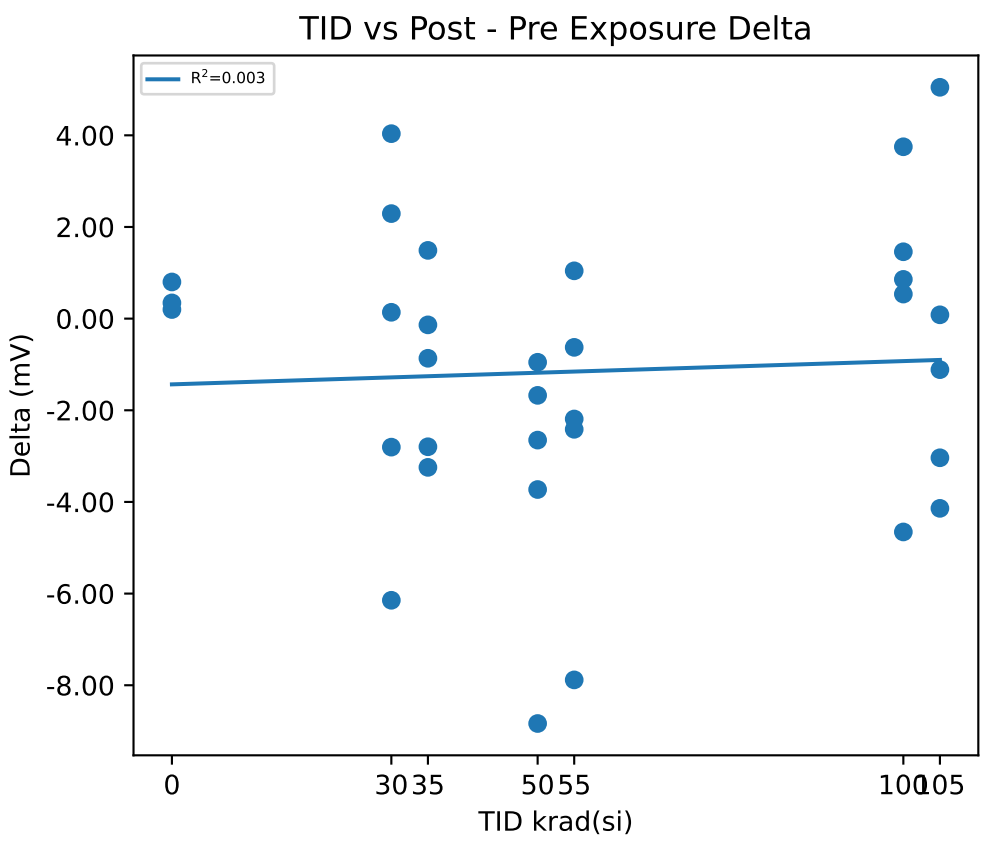
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.97	177.25	0.2844
2	0	CU2	182.52	183.29	0.7696
3	0	CU3	181.77	181.94	0.1711
11	30	Unbiased-30krad	177.58	181.58	4.0016
12	30	Unbiased-30krad	183.1	176.9	-6.2013
13	30	Unbiased-30krad	181.51	178.63	-2.8785
14	30	Unbiased-30krad	177.47	179.71	2.2478
15	30	Unbiased-30krad	179.41	179.51	0.1087
16	35	Biased-30krad	180.28	179.39	-0.8917
17	35	Biased-30krad	183.76	180.43	-3.3274
18	35	Biased-30krad	177.09	178.56	1.461
19	35	Biased-30krad	179.82	179.65	-0.177
20	35	Biased-30krad	180.34	177.51	-2.8372
30	50	Unbiased-50krad	178.3	175.59	-2.7128
31	50	Unbiased-50krad	181.09	180.07	-1.0165
32	50	Unbiased-50krad	182.4	173.5	-8.9074
33	50	Unbiased-50krad	180.29	176.51	-3.7831
34	50	Unbiased-50krad	181.98	180.27	-1.7126
40	55	Biased-50krad	177.39	178.4	1.0084
41	55	Biased-50krad	181.21	173.24	-7.9663
42	55	Biased-50krad	180.6	178.37	-2.2311
43	55	Biased-50krad	176.97	174.5	-2.4636
44	55	Biased-50krad	181.99	181.28	-0.7017
45	100	Unbiased-100krad	171.97	172.41	0.4442
46	100	Unbiased-100krad	181.08	182.5	1.4189
47	100	Unbiased-100krad	179.24	180.07	0.8261
48	100	Unbiased-100krad	182.29	177.58	-4.7115
49	100	Unbiased-100krad	177.89	181.52	3.6361
50	105	Biased-100krad	183.84	180.75	-3.0807
51	105	Biased-100krad	178.79	178.85	0.0605
52	105	Biased-100krad	179.66	178.48	-1.1766
53	105	Biased-100krad	175.84	180.83	4.996
54	105	Biased-100krad	182.15	177.97	-4.1819

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.97	180.42	182.52	3.0125	177.25	180.83	183.29	3.169	0.1711	0.40837	0.7696	0.31793
30	177.47	179.81	183.1	2.4653	176.9	179.27	181.58	1.707	-6.2013	-0.54434	4.0016	4.0724
35	177.09	180.26	183.76	2.3687	177.51	179.11	180.43	1.1157	-3.3274	-1.1545	1.461	1.9633
50	178.3	180.81	182.4	1.624	173.5	177.19	180.27	2.9344	-8.9074	-3.6265	-1.0165	3.1314
55	176.97	179.63	181.99	2.2964	173.24	177.16	181.28	3.2572	-7.9663	-2.4709	1.0084	3.3724
100	171.97	178.49	182.29	4.0216	172.41	178.82	182.5	4.033	-4.7115	0.32276	3.6361	3.0737
105	175.84	180.05	183.84	3.0916	177.97	179.38	180.83	1.3306	-4.1819	-0.67654	4.996	3.5721

Device Test: 42.23 _THRESHOLD|HYST/VIN3/////90.9/634//0///@UVLO_HYST_VIN





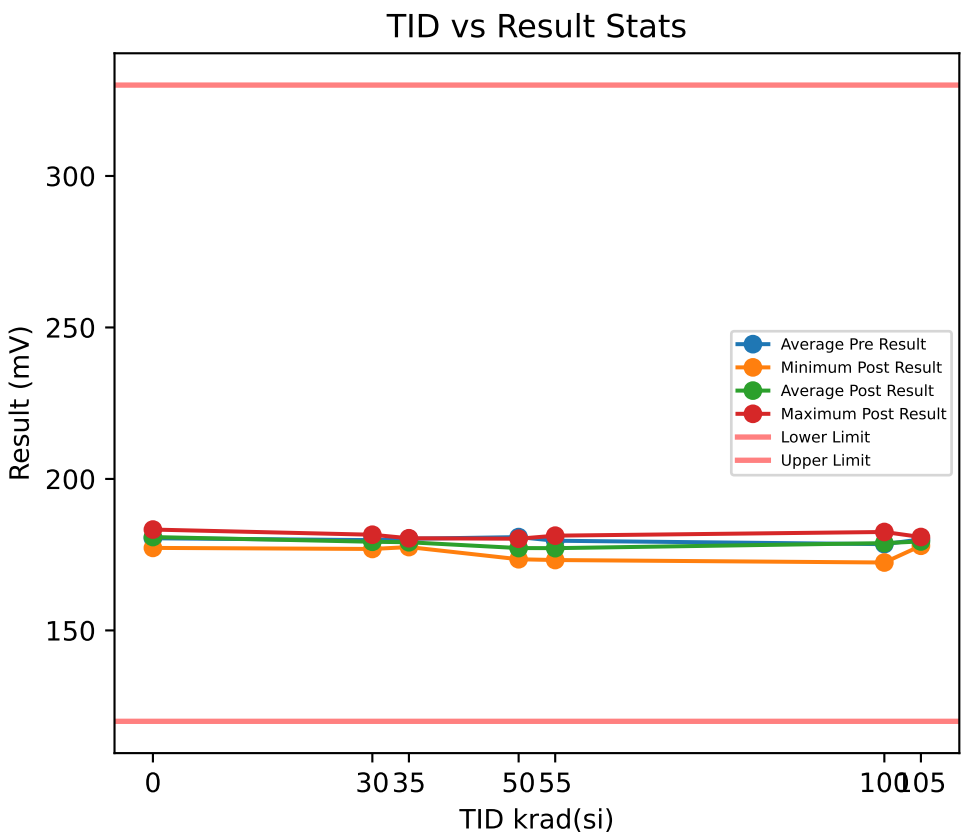
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

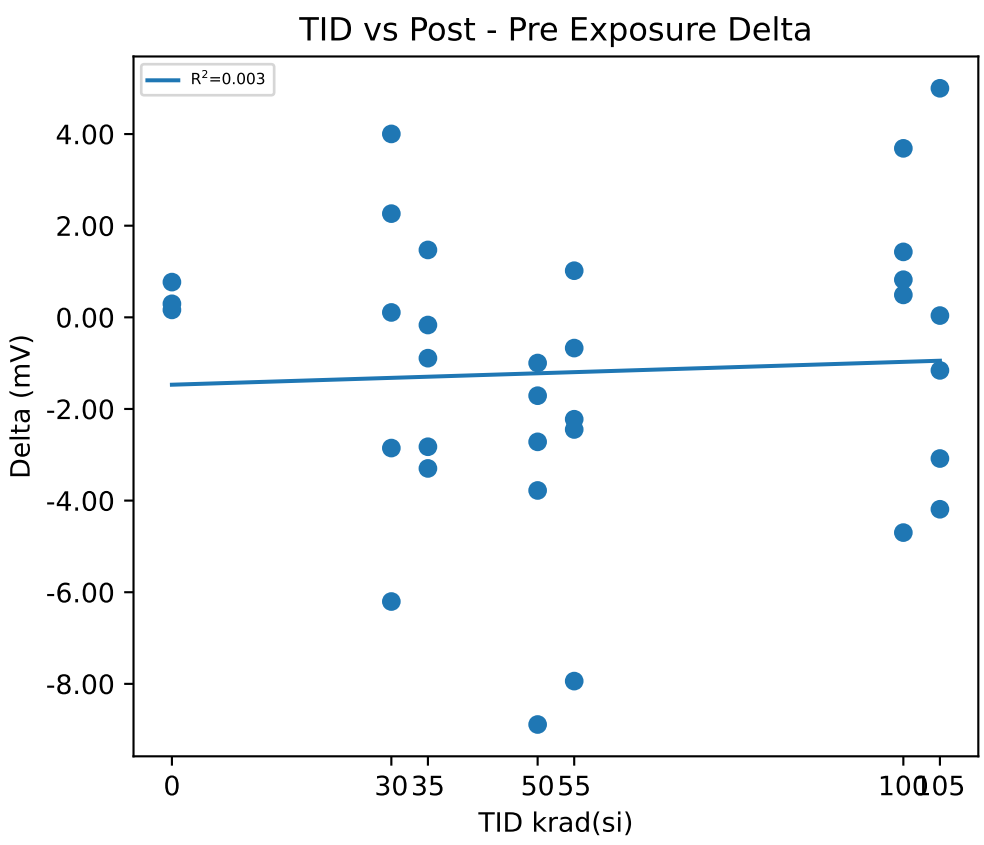
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.91	177.25	0.3431
2	0	CU2	182.51	183.31	0.7999
3	0	CU3	181.75	181.95	0.1987
11	30	Unbiased-30krad	177.56	181.6	4.0361
12	30	Unbiased-30krad	183.05	176.9	-6.1459
13	30	Unbiased-30krad	181.43	178.63	-2.8041
14	30	Unbiased-30krad	177.45	179.74	2.2918
15	30	Unbiased-30krad	179.39	179.53	0.1384
16	35	Biased-30krad	180.25	179.39	-0.8652
17	35	Biased-30krad	183.68	180.44	-3.2457
18	35	Biased-30krad	177.07	178.56	1.4891
19	35	Biased-30krad	179.78	179.65	-0.1362
20	35	Biased-30krad	180.32	177.52	-2.796
30	50	Unbiased-50krad	178.25	175.6	-2.6507
31	50	Unbiased-50krad	181.03	180.08	-0.9524
32	50	Unbiased-50krad	182.33	173.5	-8.8349
33	50	Unbiased-50krad	180.24	176.51	-3.729
34	50	Unbiased-50krad	181.94	180.27	-1.6744
40	55	Biased-50krad	177.37	178.41	1.043
41	55	Biased-50krad	181.12	173.24	-7.8833
42	55	Biased-50krad	180.57	178.38	-2.19
43	55	Biased-50krad	176.91	174.5	-2.4152
44	55	Biased-50krad	181.92	181.29	-0.6269
45	100	Unbiased-100krad	171.89	172.42	0.5358
46	100	Unbiased-100krad	181.04	182.5	1.4591
47	100	Unbiased-100krad	179.22	180.08	0.8564
48	100	Unbiased-100krad	182.24	177.59	-4.655
49	100	Unbiased-100krad	177.8	181.55	3.7501
50	105	Biased-100krad	183.81	180.78	-3.0363
51	105	Biased-100krad	178.78	178.86	0.0833
52	105	Biased-100krad	179.61	178.5	-1.1134
53	105	Biased-100krad	175.79	180.84	5.048
54	105	Biased-100krad	182.11	177.97	-4.14

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.91	180.39	182.51	3.0387	177.25	180.84	183.31	3.1786	0.1987	0.44723	0.7999	0.31384
30	177.45	179.78	183.05	2.4469	176.9	179.28	181.6	1.7108	-6.1459	-0.49674	4.0361	4.0609
35	177.07	180.22	183.68	2.3506	177.52	179.11	180.44	1.1134	-3.2457	-1.1108	1.4891	1.9473
50	178.25	180.76	182.33	1.6217	173.5	177.19	180.27	2.9353	-8.8349	-3.5683	-0.9524	3.1239
55	176.91	179.58	181.92	2.2819	173.24	177.16	181.29	3.2634	-7.8833	-2.4145	1.043	3.3581
100	171.89	178.44	182.24	4.0369	172.42	178.83	182.5	4.0326	-4.655	0.38928	3.7501	3.0872
105	175.79	180.02	183.81	3.0954	177.97	179.39	180.84	1.3358	-4.14	-0.63168	5.048	3.574

Device Test: 42.24 _THRESHOLD|HYST/VIN4/////90.9/634//0///@UVLO_HYST_VIN





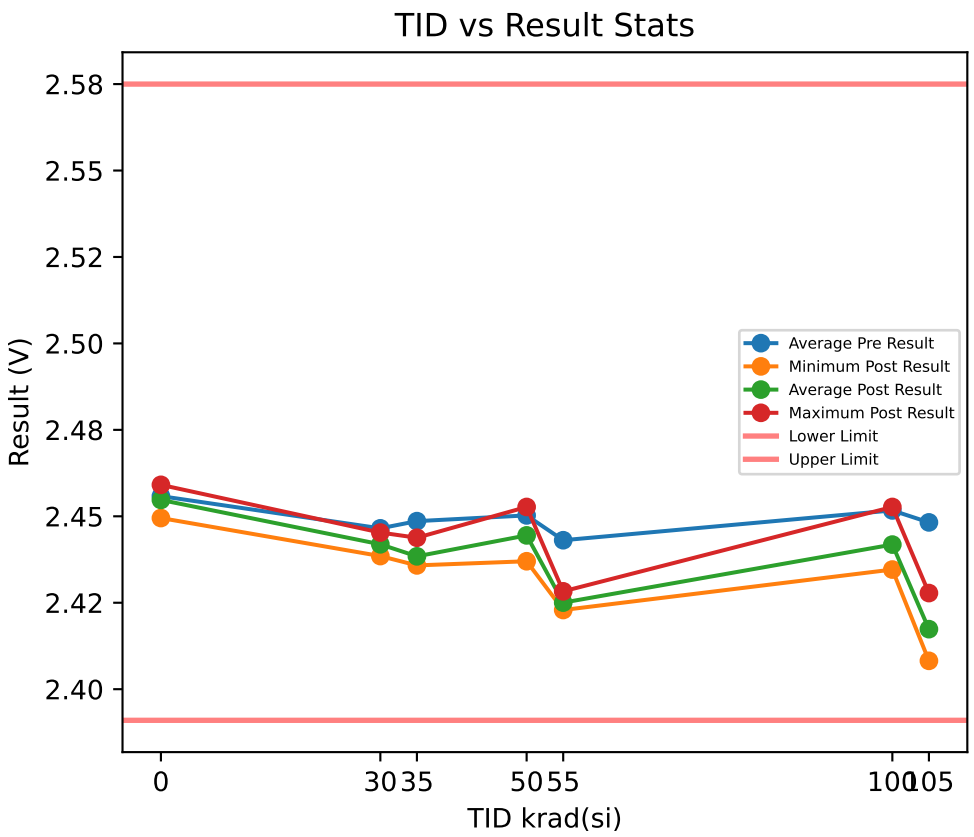
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

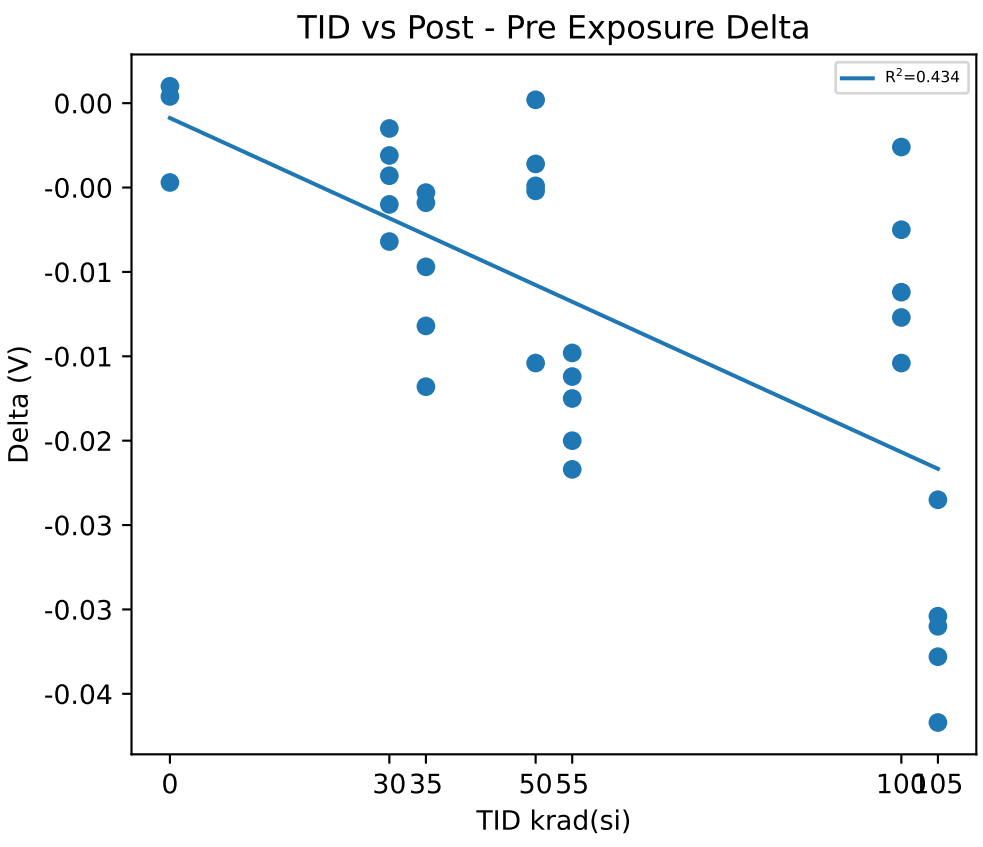
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.94	177.24	0.2951
2	0	CU2	182.52	183.29	0.7689
3	0	CU3	181.77	181.93	0.1622
11	30	Unbiased-30krad	177.58	181.58	4.003
12	30	Unbiased-30krad	183.09	176.89	-6.2027
13	30	Unbiased-30krad	181.47	178.62	-2.8534
14	30	Unbiased-30krad	177.46	179.73	2.2633
15	30	Unbiased-30krad	179.4	179.51	0.1066
16	35	Biased-30krad	180.27	179.38	-0.8914
17	35	Biased-30krad	183.72	180.42	-3.2979
18	35	Biased-30krad	177.08	178.55	1.4707
19	35	Biased-30krad	179.81	179.64	-0.1679
20	35	Biased-30krad	180.33	177.51	-2.8247
30	50	Unbiased-50krad	178.31	175.59	-2.7177
31	50	Unbiased-50krad	181.07	180.08	-0.9973
32	50	Unbiased-50krad	182.38	173.49	-8.8871
33	50	Unbiased-50krad	180.29	176.51	-3.7788
34	50	Unbiased-50krad	181.97	180.26	-1.7105
40	55	Biased-50krad	177.37	178.39	1.0177
41	55	Biased-50krad	181.17	173.23	-7.9398
42	55	Biased-50krad	180.58	178.36	-2.2243
43	55	Biased-50krad	176.95	174.5	-2.4478
44	55	Biased-50krad	181.95	181.28	-0.6711
45	100	Unbiased-100krad	171.93	172.42	0.4896
46	100	Unbiased-100krad	181.06	182.49	1.4283
47	100	Unbiased-100krad	179.24	180.06	0.8209
48	100	Unbiased-100krad	182.27	177.58	-4.6985
49	100	Unbiased-100krad	177.85	181.54	3.6881
50	105	Biased-100krad	183.83	180.75	-3.0817
51	105	Biased-100krad	178.8	178.84	0.0384
52	105	Biased-100krad	179.64	178.48	-1.158
53	105	Biased-100krad	175.83	180.83	4.999
54	105	Biased-100krad	182.13	177.94	-4.1892

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.94	180.41	182.52	3.028	177.24	180.82	183.29	3.1764	0.1622	0.40873	0.7689	0.31891
30	177.46	179.8	183.09	2.457	176.89	179.26	181.58	1.7123	-6.2027	-0.53664	4.003	4.0723
35	177.08	180.24	183.72	2.3608	177.51	179.1	180.42	1.1129	-3.2979	-1.1422	1.4707	1.9569
50	178.31	180.8	182.38	1.6145	173.49	177.18	180.26	2.9363	-8.8871	-3.6183	-0.9973	3.1268
55	176.95	179.6	181.95	2.2873	173.23	177.15	181.28	3.2554	-7.9398	-2.4531	1.0177	3.3682
100	171.93	178.47	182.27	4.03	172.42	178.82	182.49	4.0298	-4.6985	0.34568	3.6881	3.0836
105	175.83	180.04	183.83	3.089	177.94	179.37	180.83	1.338	-4.1892	-0.6783	4.999	3.5735

Device Test: 42.3 _THRESHOLD|RISE/PVIN3/////90.9/634//0///@UVLO_RISE_PVIN





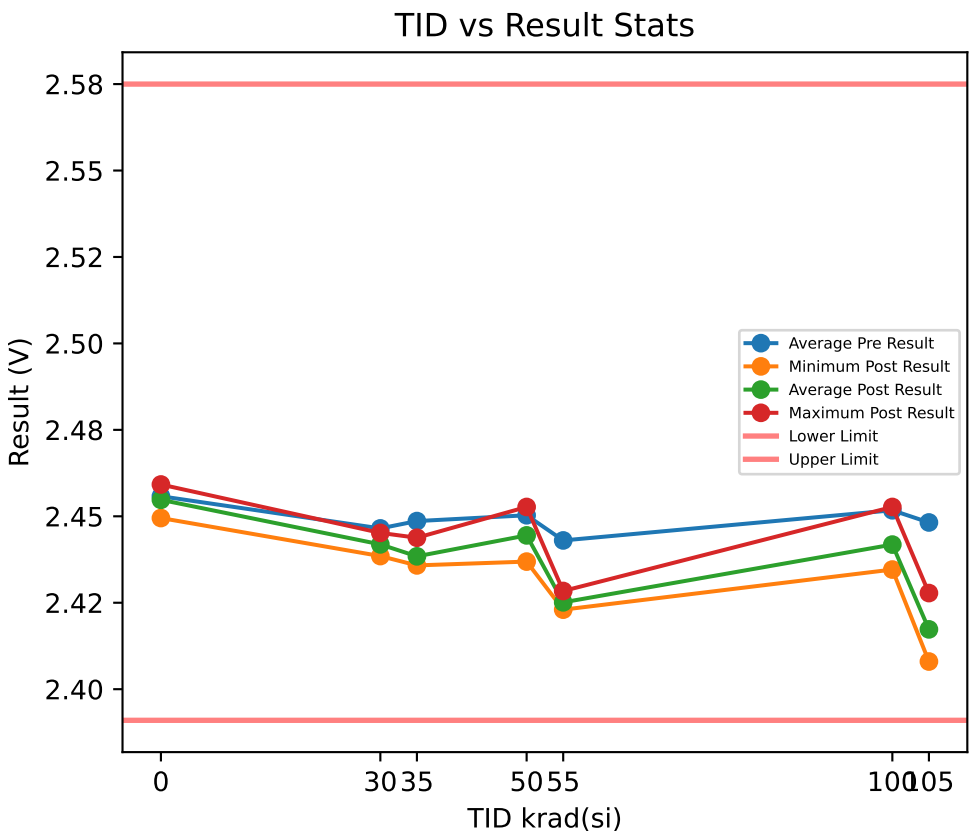
Test Results (Lower Limit = 2.391, Upper Limit = 2.575 (V))

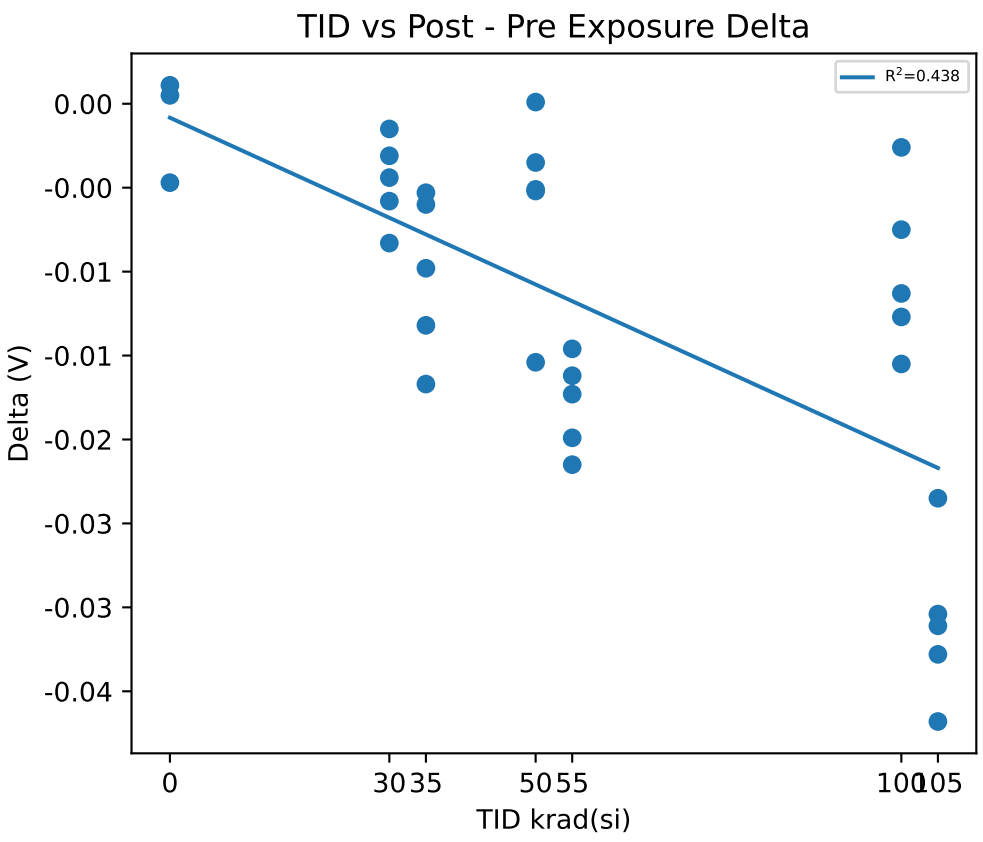
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4587	2.4591	0.0004
2	0	CU2	2.4485	2.4495	0.001
3	0	CU3	2.4603	2.4556	-0.0047
11	30	Unbiased-30krad	2.4417	2.4402	-0.0015
12	30	Unbiased-30krad	2.4497	2.4437	-0.006
13	30	Unbiased-30krad	2.4496	2.4453	-0.0043
14	30	Unbiased-30krad	2.45	2.4418	-0.0082
15	30	Unbiased-30krad	2.4416	2.4385	-0.0031
16	35	Biased-30krad	2.4497	2.4438	-0.0059
17	35	Biased-30krad	2.4495	2.4363	-0.0132
18	35	Biased-30krad	2.442	2.4367	-0.0053
19	35	Biased-30krad	2.4492	2.4395	-0.0097
20	35	Biased-30krad	2.4526	2.4358	-0.0168
30	50	Unbiased-50krad	2.4544	2.439	-0.0154
31	50	Unbiased-50krad	2.4419	2.437	-0.0049
32	50	Unbiased-50krad	2.4506	2.4454	-0.0052
33	50	Unbiased-50krad	2.4563	2.4527	-0.0036
34	50	Unbiased-50krad	2.4481	2.4483	0.0002
40	55	Biased-50krad	2.4384	2.4236	-0.0148
41	55	Biased-50krad	2.4404	2.4229	-0.0175
42	55	Biased-50krad	2.4483	2.4283	-0.02
43	55	Biased-50krad	2.4467	2.425	-0.0217
44	55	Biased-50krad	2.4416	2.4254	-0.0162
45	100	Unbiased-100krad	2.4372	2.4346	-0.0026
46	100	Unbiased-100krad	2.4654	2.4527	-0.0127
47	100	Unbiased-100krad	2.4494	2.4382	-0.0112
48	100	Unbiased-100krad	2.4507	2.4353	-0.0154
49	100	Unbiased-100krad	2.4558	2.4483	-0.0075
50	105	Biased-100krad	2.4392	2.4082	-0.031
51	105	Biased-100krad	2.4513	2.4278	-0.0235
52	105	Biased-100krad	2.4515	2.4187	-0.0328
53	105	Biased-100krad	2.4494	2.4127	-0.0367
54	105	Biased-100krad	2.4498	2.4194	-0.0304

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4485	2.4558	2.4603	0.006401	2.4495	2.4547	2.4591	0.0048583	-0.0047	-0.0011	0.001	0.0031321
30	2.4416	2.4465	2.45	0.0044483	2.4385	2.4419	2.4453	0.0027046	-0.0082	-0.00462	-0.0015	0.0025917
35	2.442	2.4486	2.4526	0.0039351	2.4358	2.4384	2.4438	0.0033327	-0.0168	-0.01018	-0.0053	0.0048813
50	2.4419	2.4503	2.4563	0.0056633	2.437	2.4445	2.4527	0.0064998	-0.0154	-0.00578	0.0002	0.0057915
55	2.4384	2.4431	2.4483	0.0042317	2.4229	2.425	2.4283	0.0020864	-0.0217	-0.01804	-0.0148	0.0028023
100	2.4372	2.4517	2.4654	0.01026	2.4346	2.4418	2.4527	0.008187	-0.0154	-0.00988	-0.0026	0.0049706
105	2.4392	2.4482	2.4515	0.0051355	2.4082	2.4174	2.4278	0.0074258	-0.0367	-0.03088	-0.0235	0.0048028

Device Test: 42.4 _THRESHOLD|RISE/PVIN4/////90.9/634//0///@UVLO_RISE_PVIN





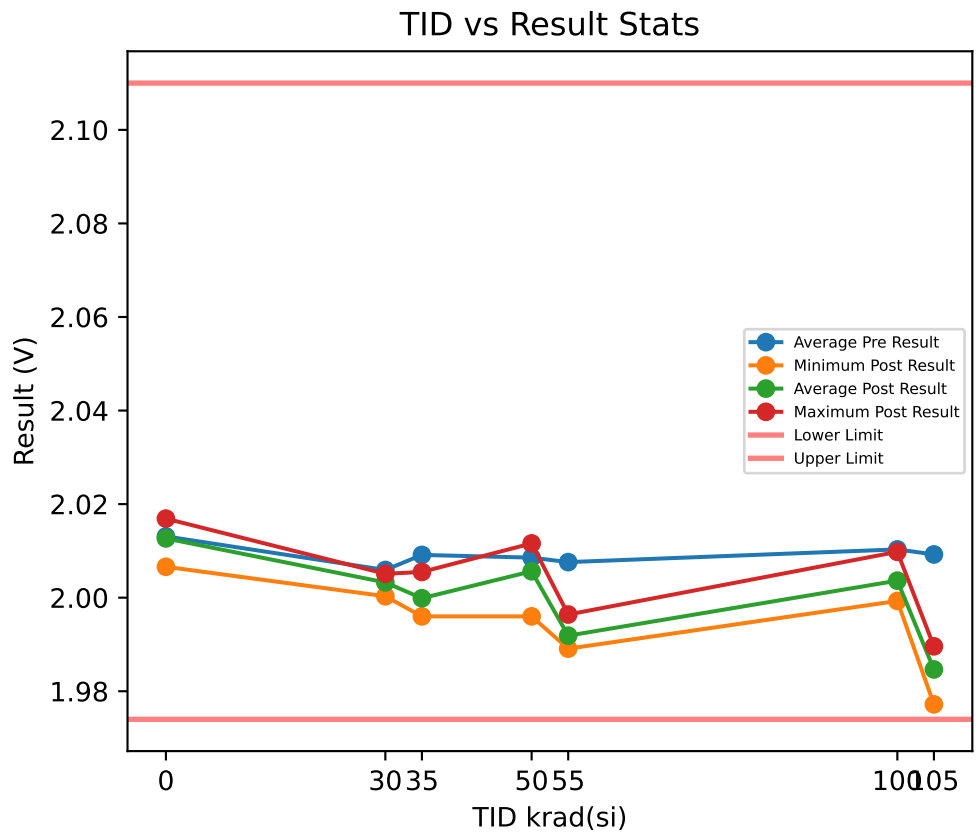
Test Results (Lower Limit = 2.391, Upper Limit = 2.575 (V))

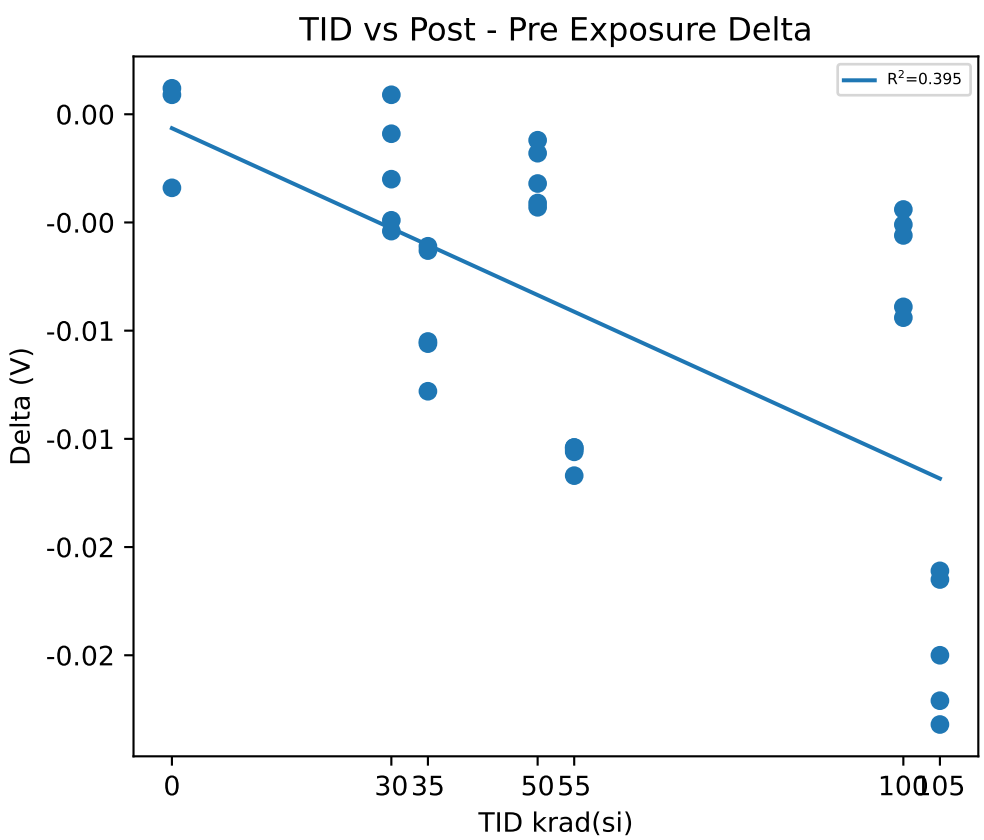
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4587	2.4592	0.0005
2	0	CU2	2.4484	2.4495	0.0011
3	0	CU3	2.4603	2.4556	-0.0047
11	30	Unbiased-30krad	2.4417	2.4402	-0.0015
12	30	Unbiased-30krad	2.4495	2.4437	-0.0058
13	30	Unbiased-30krad	2.4496	2.4452	-0.0044
14	30	Unbiased-30krad	2.4501	2.4418	-0.0083
15	30	Unbiased-30krad	2.4416	2.4385	-0.0031
16	35	Biased-30krad	2.4498	2.4438	-0.006
17	35	Biased-30krad	2.4495	2.4363	-0.0132
18	35	Biased-30krad	2.442	2.4367	-0.0053
19	35	Biased-30krad	2.4493	2.4395	-0.0098
20	35	Biased-30krad	2.4525	2.4358	-0.0167
30	50	Unbiased-50krad	2.4545	2.4391	-0.0154
31	50	Unbiased-50krad	2.442	2.4369	-0.0051
32	50	Unbiased-50krad	2.4506	2.4454	-0.0052
33	50	Unbiased-50krad	2.4562	2.4527	-0.0035
34	50	Unbiased-50krad	2.4482	2.4483	0.0001
40	55	Biased-50krad	2.4383	2.4237	-0.0146
41	55	Biased-50krad	2.4403	2.423	-0.0173
42	55	Biased-50krad	2.4483	2.4284	-0.0199
43	55	Biased-50krad	2.4466	2.4251	-0.0215
44	55	Biased-50krad	2.4416	2.4254	-0.0162
45	100	Unbiased-100krad	2.4372	2.4346	-0.0026
46	100	Unbiased-100krad	2.4654	2.4527	-0.0127
47	100	Unbiased-100krad	2.4495	2.4382	-0.0113
48	100	Unbiased-100krad	2.4508	2.4353	-0.0155
49	100	Unbiased-100krad	2.4558	2.4483	-0.0075
50	105	Biased-100krad	2.4391	2.408	-0.0311
51	105	Biased-100krad	2.4513	2.4278	-0.0235
52	105	Biased-100krad	2.4515	2.4187	-0.0328
53	105	Biased-100krad	2.4495	2.4127	-0.0368
54	105	Biased-100krad	2.4497	2.4193	-0.0304

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4484	2.4558	2.4603	0.0064583	2.4495	2.4548	2.4592	0.0049034	-0.0047	-0.0010333	0.0011	0.0031896
30	2.4416	2.4465	2.4501	0.0044334	2.4385	2.4419	2.4452	0.0026734	-0.0083	-0.00462	-0.0015	0.0025994
35	2.442	2.4486	2.4525	0.0039214	2.4358	2.4384	2.4438	0.0033327	-0.0167	-0.0102	-0.0053	0.0048234
50	2.442	2.4503	2.4562	0.0056089	2.4369	2.4445	2.4527	0.0065078	-0.0154	-0.00582	0.0001	0.0057686
55	2.4383	2.443	2.4483	0.0042541	2.423	2.4251	2.4284	0.0020825	-0.0215	-0.0179	-0.0146	0.0027884
100	2.4372	2.4517	2.4654	0.010252	2.4346	2.4418	2.4527	0.008187	-0.0155	-0.00992	-0.0026	0.0050052
105	2.4391	2.4482	2.4515	0.005178	2.408	2.4173	2.4278	0.007481	-0.0368	-0.03092	-0.0235	0.0048339

Device Test: 42.5 _THRESHOLD|FALL/PVIN1////90.9/634//0///@UVLO_FALL_PVIN





Test Results (Lower Limit = 1.974, Upper Limit = 2.11 (V))

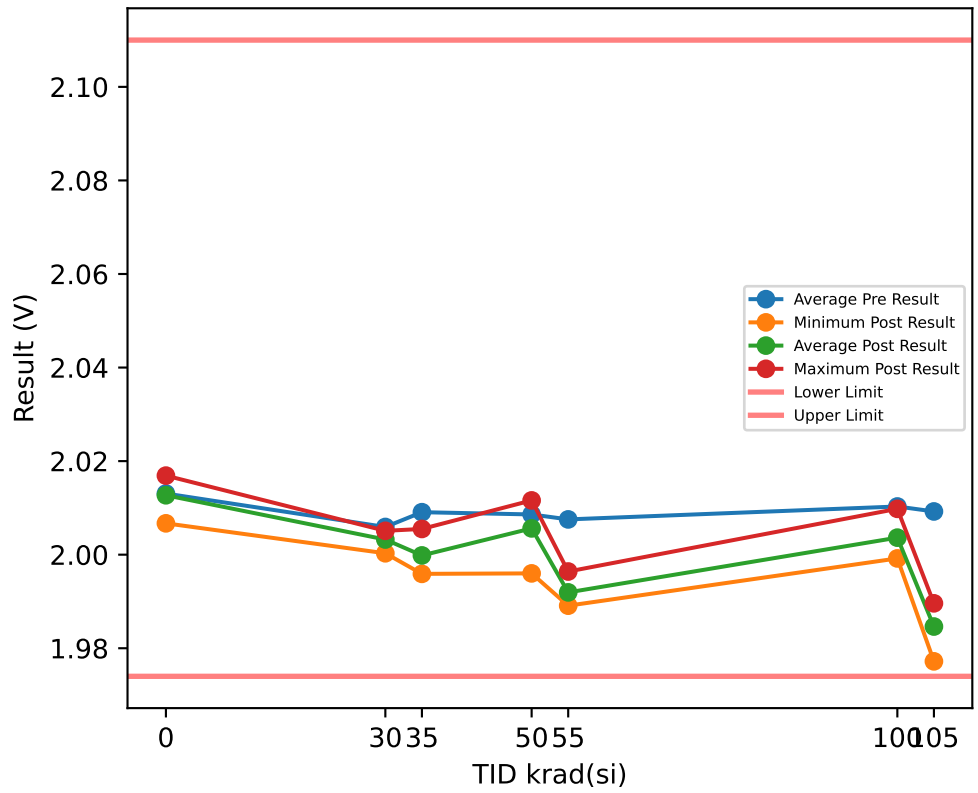
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0157	2.0169	0.0012
2	0	CU2	2.01	2.0066	-0.0034
3	0	CU3	2.0136	2.0145	0.0009
11	30	Unbiased-30krad	1.9994	2.0003	0.0009
12	30	Unbiased-30krad	2.0098	2.0049	-0.0049
13	30	Unbiased-30krad	2.0081	2.0051	-0.003
14	30	Unbiased-30krad	2.0059	2.005	-0.0009
15	30	Unbiased-30krad	2.0064	2.001	-0.0054
16	35	Biased-30krad	2.0102	1.9997	-0.0105
17	35	Biased-30krad	2.005	1.9987	-0.0063
18	35	Biased-30krad	2.0021	1.996	-0.0061
19	35	Biased-30krad	2.0161	2.0055	-0.0106
20	35	Biased-30krad	2.0123	1.9995	-0.0128
30	50	Unbiased-50krad	2.0128	2.0116	-0.0012
31	50	Unbiased-50krad	2.0003	1.996	-0.0043
32	50	Unbiased-50krad	2.0129	2.0097	-0.0032
33	50	Unbiased-50krad	2.0093	2.0075	-0.0018
34	50	Unbiased-50krad	2.0075	2.0034	-0.0041
40	55	Biased-50krad	2.0045	1.9891	-0.0154
41	55	Biased-50krad	2.0081	1.9925	-0.0156
42	55	Biased-50krad	2.0119	1.9964	-0.0155
43	55	Biased-50krad	2.0088	1.9921	-0.0167
44	55	Biased-50krad	2.0047	1.9893	-0.0154
45	100	Unbiased-100krad	2.0053	2.0002	-0.0051
46	100	Unbiased-100krad	2.0154	2.0098	-0.0056
47	100	Unbiased-100krad	2.0087	1.9993	-0.0094
48	100	Unbiased-100krad	2.0113	2.0024	-0.0089
49	100	Unbiased-100krad	2.0109	2.0065	-0.0044
50	105	Biased-100krad	2.0085	1.987	-0.0215
51	105	Biased-100krad	2.0167	1.9896	-0.0271
52	105	Biased-100krad	2.006	1.981	-0.025
53	105	Biased-100krad	2.0054	1.9772	-0.0282
54	105	Biased-100krad	2.0096	1.9885	-0.0211

Test Statistics (V)

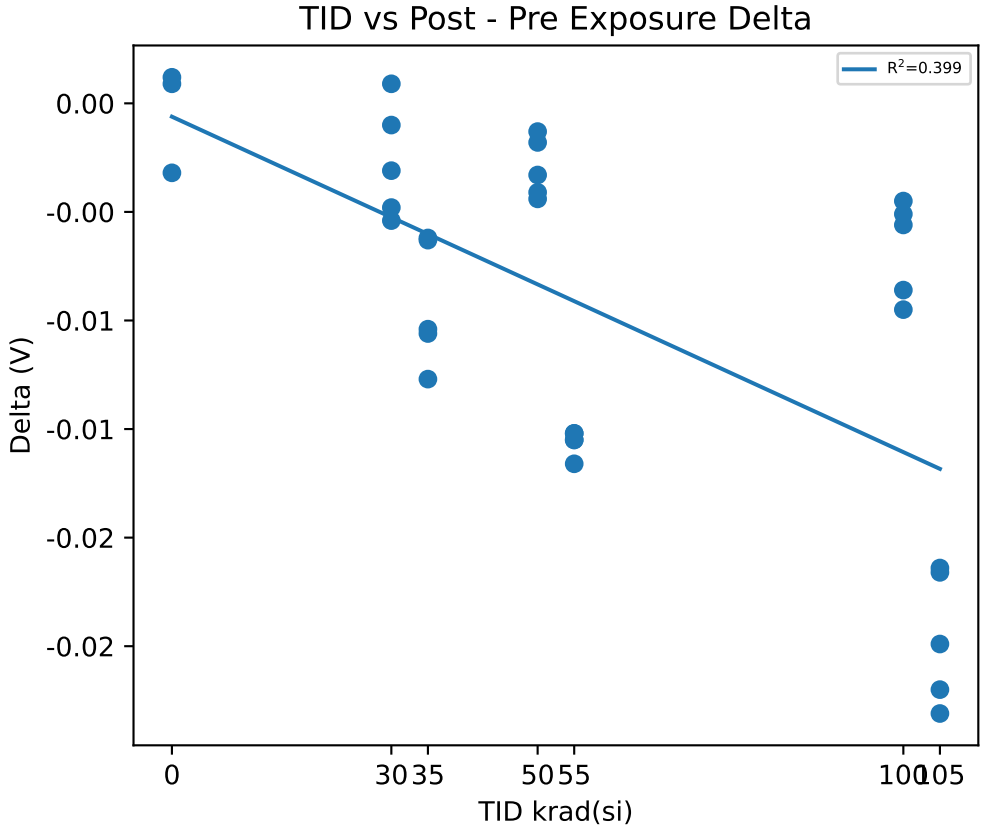
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.01	2.0131	2.0157	0.0028827	2.0066	2.0127	2.0169	0.0053892	-0.0034	-0.00043333	0.0012	0.0025736
30	1.9994	2.0059	2.0098	0.0039544	2.0003	2.0033	2.0051	0.0023965	-0.0054	-0.00266	0.0009	0.0026651
35	2.0021	2.0091	2.0161	0.0056181	1.996	1.9999	2.0055	0.0034716	-0.0128	-0.00926	-0.0061	0.0029416
50	2.0003	2.0086	2.0129	0.0051651	1.996	2.0056	2.0116	0.006193	-0.0043	-0.00292	-0.0012	0.0013773
55	2.0045	2.0076	2.0119	0.0030903	1.9891	1.9919	1.9964	0.0029685	-0.0167	-0.01572	-0.0154	0.00055408
100	2.0053	2.0103	2.0154	0.0037057	1.9993	2.0036	2.0098	0.0044253	-0.0094	-0.00668	-0.0044	0.0023015
105	2.0054	2.0092	2.0167	0.0045159	1.9772	1.9847	1.9896	0.0053309	-0.0282	-0.02458	-0.0211	0.0032105

Device Test: 42.6 _THRESHOLD|FALL/PVIN2/////90.9/634//0///@UVLO_FALL_PVIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.974, Upper Limit = 2.11 (V))

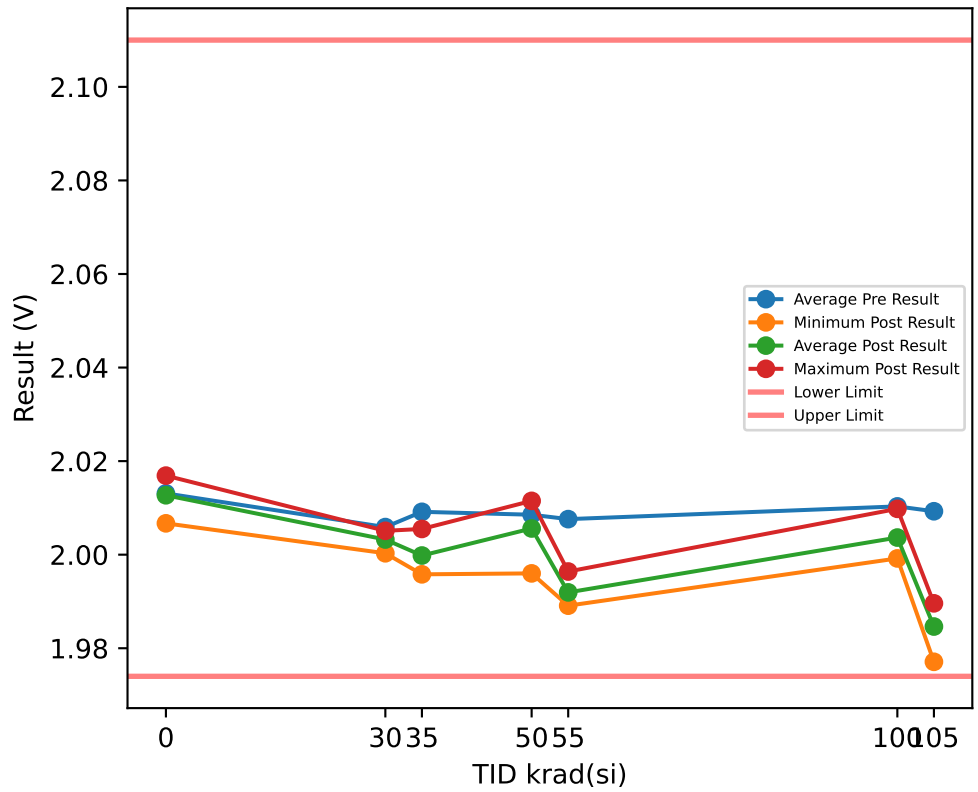
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0157	2.0169	0.0012
2	0	CU2	2.0099	2.0067	-0.0032
3	0	CU3	2.0136	2.0145	0.0009
11	30	Unbiased-30krad	1.9994	2.0003	0.0009
12	30	Unbiased-30krad	2.0097	2.0049	-0.0048
13	30	Unbiased-30krad	2.0082	2.0051	-0.0031
14	30	Unbiased-30krad	2.0059	2.0049	-0.001
15	30	Unbiased-30krad	2.0064	2.001	-0.0054
16	35	Biased-30krad	2.0101	1.9997	-0.0104
17	35	Biased-30krad	2.005	1.9987	-0.0063
18	35	Biased-30krad	2.0021	1.9959	-0.0062
19	35	Biased-30krad	2.0161	2.0055	-0.0106
20	35	Biased-30krad	2.0121	1.9994	-0.0127
30	50	Unbiased-50krad	2.0129	2.0116	-0.0013
31	50	Unbiased-50krad	2.0004	1.996	-0.0044
32	50	Unbiased-50krad	2.0129	2.0096	-0.0033
33	50	Unbiased-50krad	2.0093	2.0075	-0.0018
34	50	Unbiased-50krad	2.0075	2.0034	-0.0041
40	55	Biased-50krad	2.0043	1.9891	-0.0152
41	55	Biased-50krad	2.0081	1.9926	-0.0155
42	55	Biased-50krad	2.0119	1.9964	-0.0155
43	55	Biased-50krad	2.0088	1.9922	-0.0166
44	55	Biased-50krad	2.0046	1.9894	-0.0152
45	100	Unbiased-100krad	2.0053	2.0002	-0.0051
46	100	Unbiased-100krad	2.0154	2.0098	-0.0056
47	100	Unbiased-100krad	2.0087	1.9992	-0.0095
48	100	Unbiased-100krad	2.0111	2.0025	-0.0086
49	100	Unbiased-100krad	2.011	2.0065	-0.0045
50	105	Biased-100krad	2.0086	1.987	-0.0216
51	105	Biased-100krad	2.0166	1.9896	-0.027
52	105	Biased-100krad	2.006	1.9811	-0.0249
53	105	Biased-100krad	2.0053	1.9772	-0.0281
54	105	Biased-100krad	2.0097	1.9883	-0.0214

Test Statistics (V)

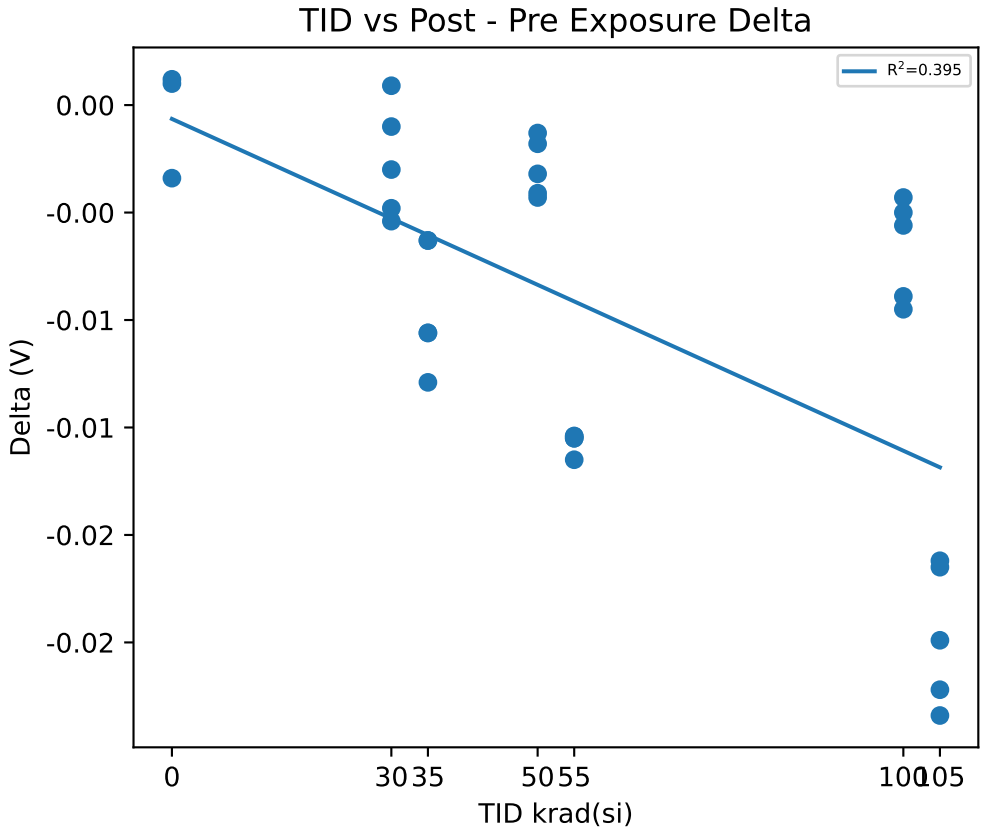
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0099	2.0131	2.0157	0.0029366	2.0067	2.0127	2.0169	0.0053329	-0.0032	-0.00036667	0.0012	0.0024583
30	1.9994	2.0059	2.0097	0.0039442	2.0003	2.0032	2.0051	0.0023787	-0.0054	-0.00268	0.0009	0.0026319
35	2.0021	2.0091	2.0161	0.0055859	1.9959	1.9998	2.0055	0.0035026	-0.0127	-0.00924	-0.0062	0.0028745
50	2.0004	2.0086	2.0129	0.0051459	1.996	2.0056	2.0116	0.0061767	-0.0044	-0.00298	-0.0013	0.0013773
55	2.0043	2.0075	2.0119	0.0031643	1.9891	1.9919	1.9964	0.0029543	-0.0166	-0.0156	-0.0152	0.00057879
100	2.0053	2.0103	2.0154	0.003698	1.9992	2.0036	2.0098	0.0044433	-0.0095	-0.00666	-0.0045	0.002239
105	2.0053	2.0092	2.0166	0.0044948	1.9772	1.9846	1.9896	0.0052785	-0.0281	-0.0246	-0.0214	0.0030553

Device Test: 42.7 _THRESHOLD|FALL/PVIN3/////90.9/634//0///@UVLO_FALL_PVIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.974, Upper Limit = 2.11 (V))

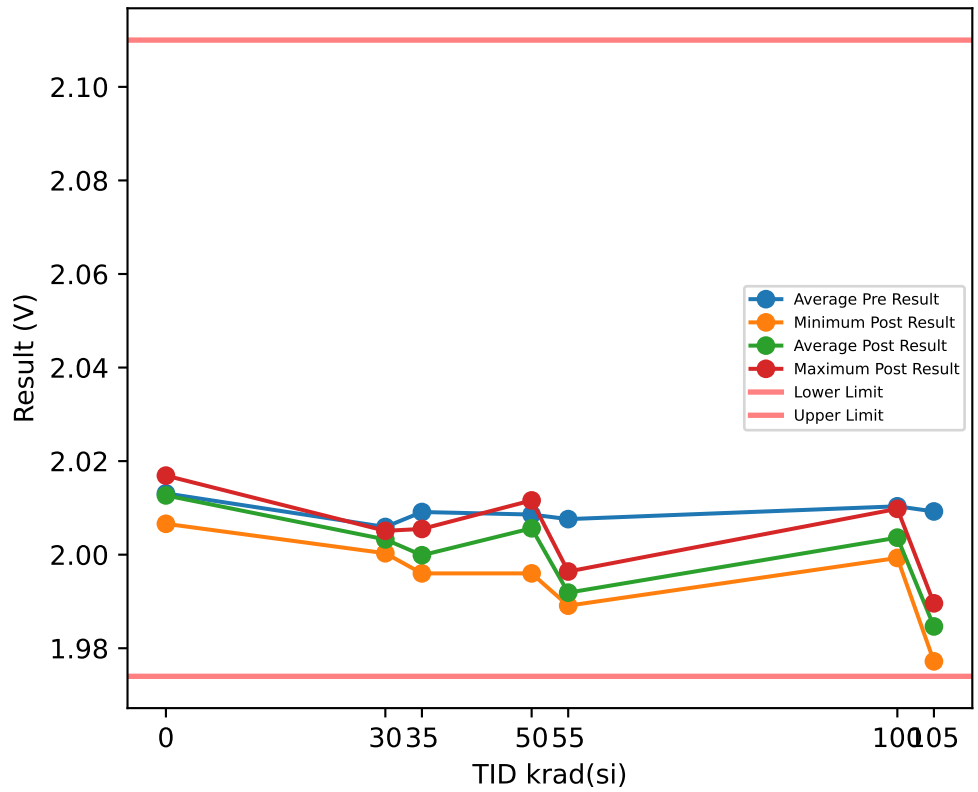
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0157	2.0169	0.0012
2	0	CU2	2.0101	2.0067	-0.0034
3	0	CU3	2.0135	2.0145	0.001
11	30	Unbiased-30krad	1.9994	2.0003	0.0009
12	30	Unbiased-30krad	2.0097	2.0049	-0.0048
13	30	Unbiased-30krad	2.0081	2.0051	-0.003
14	30	Unbiased-30krad	2.0059	2.0049	-0.001
15	30	Unbiased-30krad	2.0064	2.001	-0.0054
16	35	Biased-30krad	2.0103	1.9997	-0.0106
17	35	Biased-30krad	2.005	1.9987	-0.0063
18	35	Biased-30krad	2.0021	1.9958	-0.0063
19	35	Biased-30krad	2.0161	2.0055	-0.0106
20	35	Biased-30krad	2.0123	1.9994	-0.0129
30	50	Unbiased-50krad	2.0128	2.0115	-0.0013
31	50	Unbiased-50krad	2.0003	1.996	-0.0043
32	50	Unbiased-50krad	2.0128	2.0096	-0.0032
33	50	Unbiased-50krad	2.0093	2.0075	-0.0018
34	50	Unbiased-50krad	2.0075	2.0034	-0.0041
40	55	Biased-50krad	2.0045	1.9891	-0.0154
41	55	Biased-50krad	2.0081	1.9926	-0.0155
42	55	Biased-50krad	2.0119	1.9964	-0.0155
43	55	Biased-50krad	2.0087	1.9922	-0.0165
44	55	Biased-50krad	2.0048	1.9894	-0.0154
45	100	Unbiased-100krad	2.0052	2.0002	-0.005
46	100	Unbiased-100krad	2.0154	2.0098	-0.0056
47	100	Unbiased-100krad	2.0087	1.9992	-0.0095
48	100	Unbiased-100krad	2.0114	2.0025	-0.0089
49	100	Unbiased-100krad	2.0109	2.0066	-0.0043
50	105	Biased-100krad	2.0085	1.987	-0.0215
51	105	Biased-100krad	2.0168	1.9896	-0.0272
52	105	Biased-100krad	2.006	1.9811	-0.0249
53	105	Biased-100krad	2.0055	1.9771	-0.0284
54	105	Biased-100krad	2.0096	1.9884	-0.0212

Test Statistics (V)

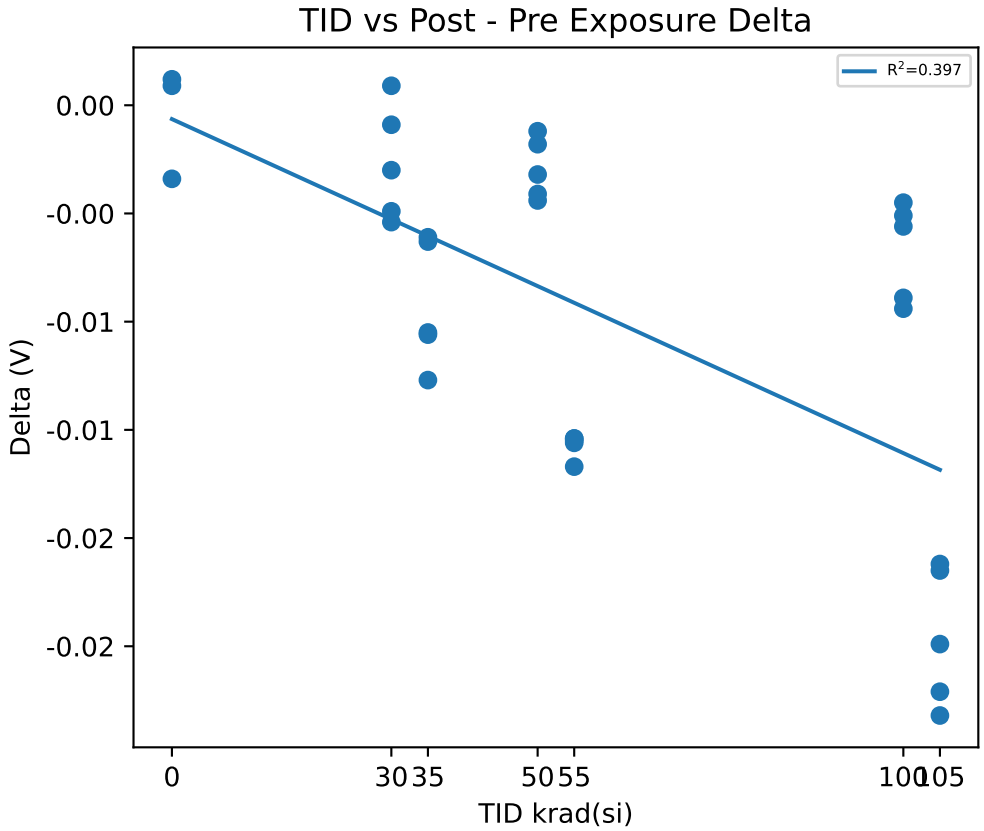
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0101	2.0131	2.0157	0.0028213	2.0067	2.0127	2.0169	0.0053329	-0.0034	-0.0004	0.0012	0.0026
30	1.9994	2.0059	2.0097	0.00393	2.0003	2.0032	2.0051	0.0023787	-0.0054	-0.00266	0.0009	0.0026283
35	2.0021	2.0092	2.0161	0.005623	1.9958	1.9998	2.0055	0.0035309	-0.0129	-0.00934	-0.0063	0.0029297
50	2.0003	2.0085	2.0128	0.0051442	1.996	2.0056	2.0115	0.0061526	-0.0043	-0.00294	-0.0013	0.0013465
55	2.0045	2.0076	2.0119	0.0030578	1.9891	1.9919	1.9964	0.0029543	-0.0165	-0.01566	-0.0154	0.00047223
100	2.0052	2.0103	2.0154	0.0037466	1.9992	2.0037	2.0098	0.0044596	-0.0095	-0.00666	-0.0043	0.0023734
105	2.0055	2.0093	2.0168	0.0045362	1.9771	1.9846	1.9896	0.0053313	-0.0284	-0.02464	-0.0212	0.0032578

Device Test: 42.8 _THRESHOLD|FALL/PVIN4/////90.9/634//0///@UVLO_FALL_PVIN

TID vs Result Stats



TID vs Post - Pre Exposure Delta



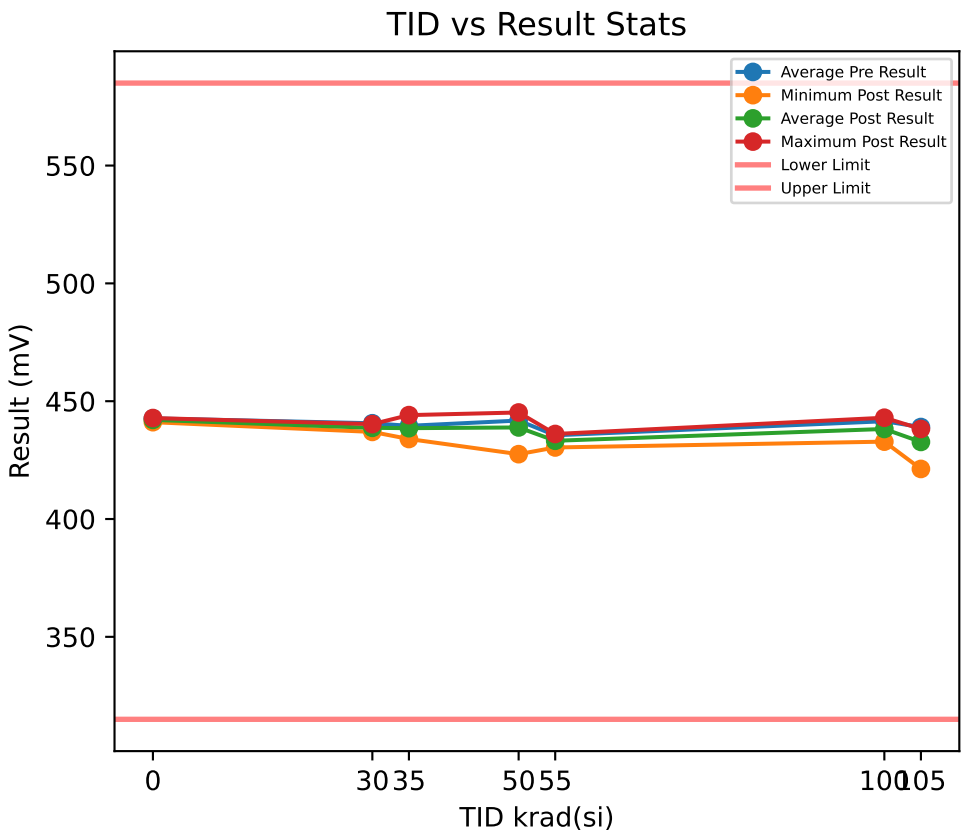
Test Results (Lower Limit = 1.974, Upper Limit = 2.11 (V))

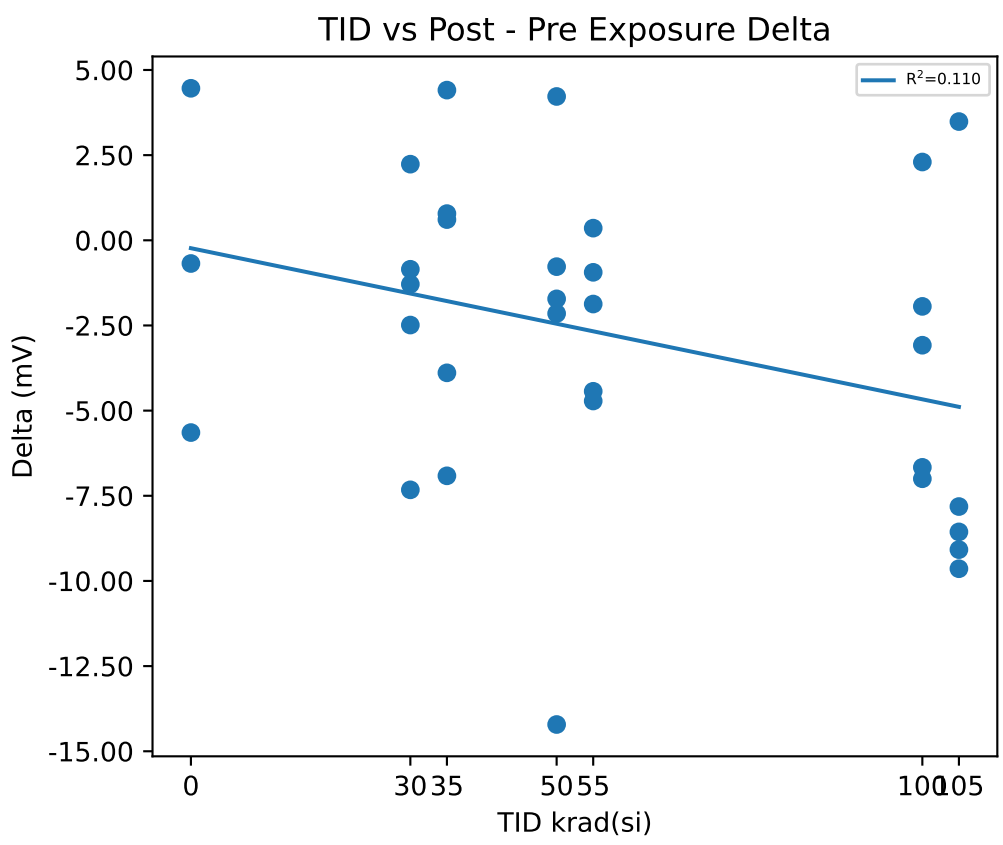
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0157	2.0169	0.0012
2	0	CU2	2.01	2.0066	-0.0034
3	0	CU3	2.0136	2.0145	0.0009
11	30	Unbiased-30krad	1.9994	2.0003	0.0009
12	30	Unbiased-30krad	2.0098	2.0049	-0.0049
13	30	Unbiased-30krad	2.0081	2.0051	-0.003
14	30	Unbiased-30krad	2.0059	2.005	-0.0009
15	30	Unbiased-30krad	2.0064	2.001	-0.0054
16	35	Biased-30krad	2.0102	1.9997	-0.0105
17	35	Biased-30krad	2.005	1.9987	-0.0063
18	35	Biased-30krad	2.0021	1.996	-0.0061
19	35	Biased-30krad	2.0161	2.0055	-0.0106
20	35	Biased-30krad	2.0122	1.9995	-0.0127
30	50	Unbiased-50krad	2.0128	2.0116	-0.0012
31	50	Unbiased-50krad	2.0004	1.996	-0.0044
32	50	Unbiased-50krad	2.0129	2.0097	-0.0032
33	50	Unbiased-50krad	2.0093	2.0075	-0.0018
34	50	Unbiased-50krad	2.0075	2.0034	-0.0041
40	55	Biased-50krad	2.0045	1.9891	-0.0154
41	55	Biased-50krad	2.0081	1.9925	-0.0156
42	55	Biased-50krad	2.0119	1.9964	-0.0155
43	55	Biased-50krad	2.0088	1.9921	-0.0167
44	55	Biased-50krad	2.0047	1.9893	-0.0154
45	100	Unbiased-100krad	2.0053	2.0002	-0.0051
46	100	Unbiased-100krad	2.0154	2.0098	-0.0056
47	100	Unbiased-100krad	2.0087	1.9993	-0.0094
48	100	Unbiased-100krad	2.0113	2.0024	-0.0089
49	100	Unbiased-100krad	2.011	2.0065	-0.0045
50	105	Biased-100krad	2.0085	1.987	-0.0215
51	105	Biased-100krad	2.0167	1.9896	-0.0271
52	105	Biased-100krad	2.006	1.9811	-0.0249
53	105	Biased-100krad	2.0054	1.9772	-0.0282
54	105	Biased-100krad	2.0096	1.9884	-0.0212

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.01	2.0131	2.0157	0.0028827	2.0066	2.0127	2.0169	0.0053892	-0.0034	-0.00043333	0.0012	0.0025736
30	1.9994	2.0059	2.0098	0.0039544	2.0003	2.0033	2.0051	0.0023965	-0.0054	-0.00266	0.0009	0.0026651
35	2.0021	2.0091	2.0161	0.0056042	1.996	1.9999	2.0055	0.0034716	-0.0127	-0.00924	-0.0061	0.0029117
50	2.0004	2.0086	2.0129	0.0051251	1.996	2.0056	2.0116	0.006193	-0.0044	-0.00294	-0.0012	0.0014029
55	2.0045	2.0076	2.0119	0.0030903	1.9891	1.9919	1.9964	0.0029685	-0.0167	-0.01572	-0.0154	0.00055408
100	2.0053	2.0103	2.0154	0.0037099	1.9993	2.0036	2.0098	0.0044253	-0.0094	-0.0067	-0.0045	0.0022771
105	2.0054	2.0092	2.0167	0.0045159	1.9772	1.9847	1.9896	0.005296	-0.0282	-0.02458	-0.0212	0.0031807

Device Test: 42.9 _THRESHOLD|HYST/PVIN1////90.9/634//0///@UVLO_HYST_PVIN





Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

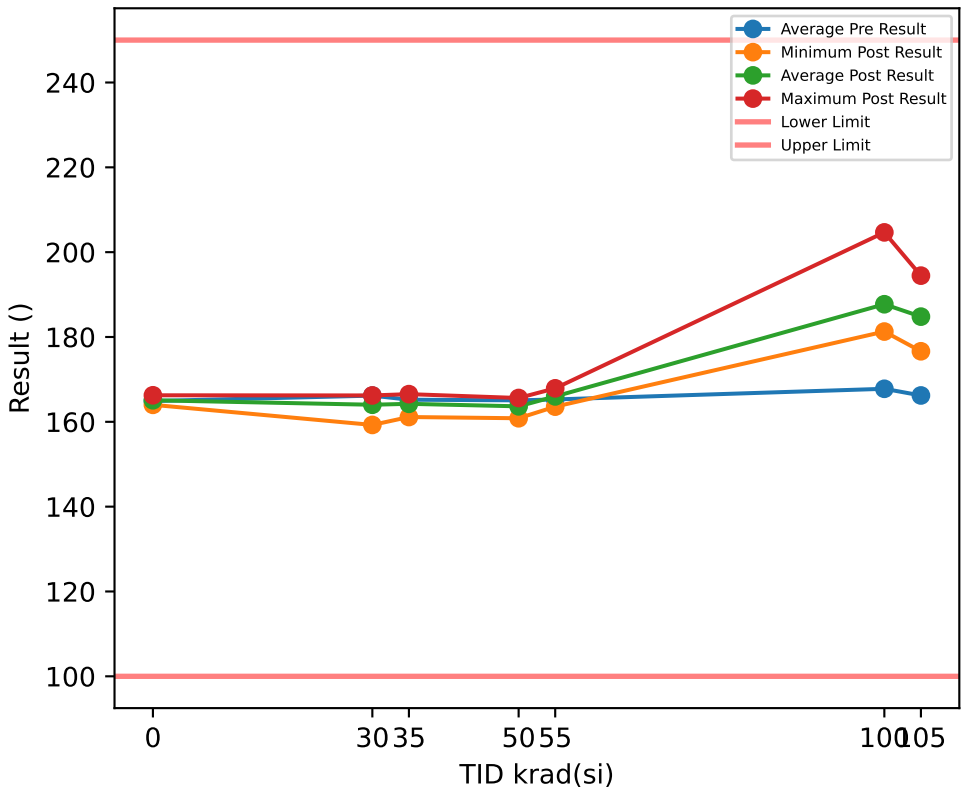
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	442.96	442.28	-0.681
2	0	CU2	438.39	442.85	4.4625
3	0	CU3	446.74	441.09	-5.644
11	30	Unbiased-30krad	442.39	439.9	-2.4878
12	30	Unbiased-30krad	439.68	438.83	-0.8505
13	30	Unbiased-30krad	441.56	440.27	-1.2885
14	30	Unbiased-30krad	444.29	436.96	-7.3254
15	30	Unbiased-30krad	435.29	437.53	2.2348
16	35	Biased-30krad	439.68	444.09	4.4088
17	35	Biased-30krad	444.52	437.6	-6.914
18	35	Biased-30krad	439.97	440.75	0.7838
19	35	Biased-30krad	433.34	433.95	0.6081
20	35	Biased-30krad	440.25	436.36	-3.8906
30	50	Unbiased-50krad	441.74	427.52	-14.215
31	50	Unbiased-50krad	441.69	440.92	-0.7736
32	50	Unbiased-50krad	437.89	435.74	-2.1488
33	50	Unbiased-50krad	446.93	445.21	-1.7192
34	50	Unbiased-50krad	440.69	444.91	4.2223
40	55	Biased-50krad	434.21	434.56	0.3569
41	55	Biased-50krad	432.23	430.36	-1.8709
42	55	Biased-50krad	436.41	431.98	-4.4327
43	55	Biased-50krad	437.75	433.04	-4.7174
44	55	Biased-50krad	437.03	436.09	-0.94
45	100	Unbiased-100krad	432.2	434.5	2.2983
46	100	Unbiased-100krad	449.99	442.99	-7.0002
47	100	Unbiased-100krad	440.93	438.99	-1.9398
48	100	Unbiased-100krad	439.5	432.83	-6.6651
49	100	Unbiased-100krad	444.85	441.77	-3.0801
50	105	Biased-100krad	430.89	421.25	-9.6413
51	105	Biased-100krad	434.73	438.22	3.4858
52	105	Biased-100krad	445.46	437.65	-7.8158
53	105	Biased-100krad	444.03	435.47	-8.5602
54	105	Biased-100krad	440.07	430.98	-9.0807

Test Statistics (mV)

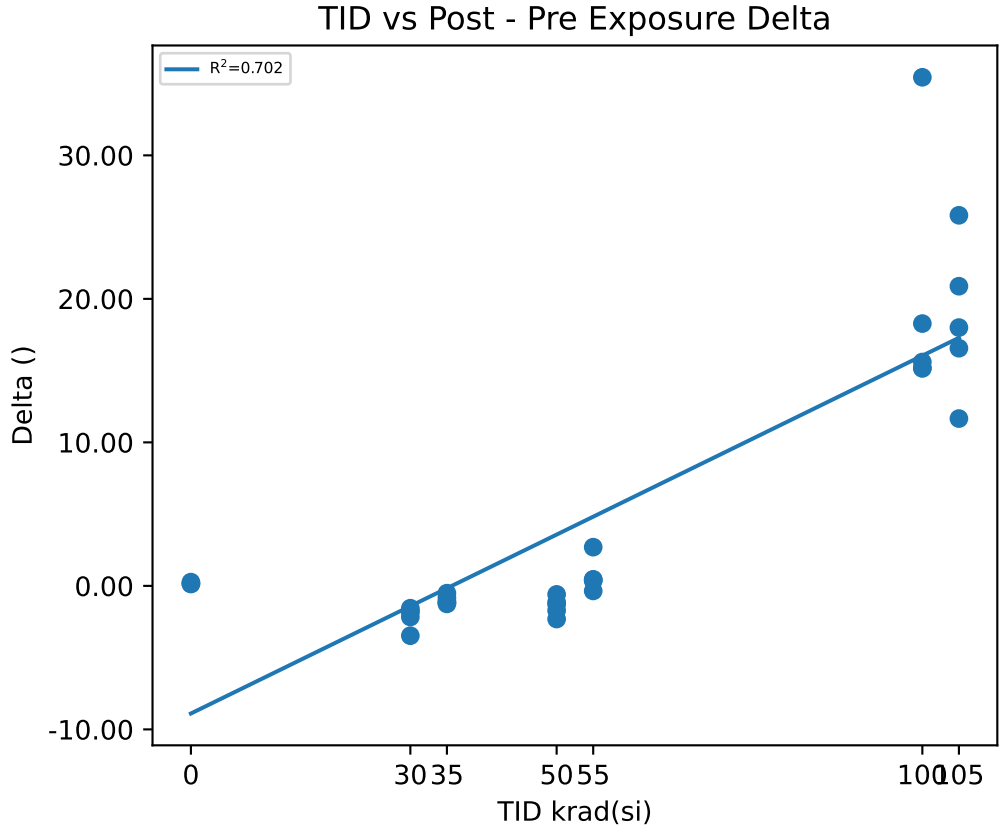
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	438.39	442.7	446.74	4.1808	441.09	442.08	442.85	0.89684	-5.644	-0.62083	4.4625	5.0535
30	435.29	440.64	444.29	3.417	436.96	438.7	440.27	1.4419	-7.3254	-1.9435	2.2348	3.4765
35	433.34	439.55	444.52	3.9967	433.95	438.55	444.09	3.9495	-6.914	-1.0008	4.4088	4.4259
50	437.89	441.79	446.93	3.2751	427.52	438.86	445.21	7.4075	-14.215	-2.9268	4.2223	6.8048
55	432.23	435.53	437.75	2.2682	430.36	433.2	436.09	2.2222	-4.7174	-2.3208	0.3569	2.207
100	432.2	441.49	449.99	6.5973	432.83	438.22	442.99	4.4378	-7.0002	-3.2774	2.2983	3.8162
105	430.89	439.04	445.46	6.1669	421.25	432.71	438.22	7.0107	-9.6413	-6.3224	3.4858	5.5241

Device Test: 45.1 _OnDeadTime|ON_TIME/SW1/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



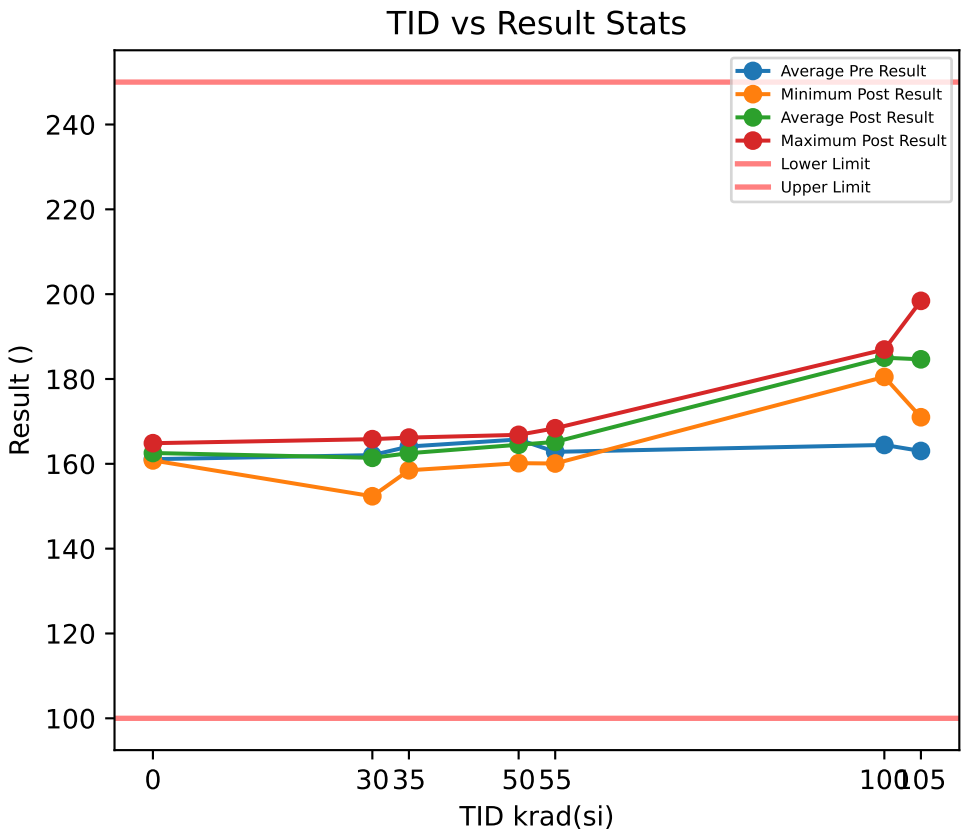
Test Results (Lower Limit = 100.0, Upper Limit = 250.0 ())

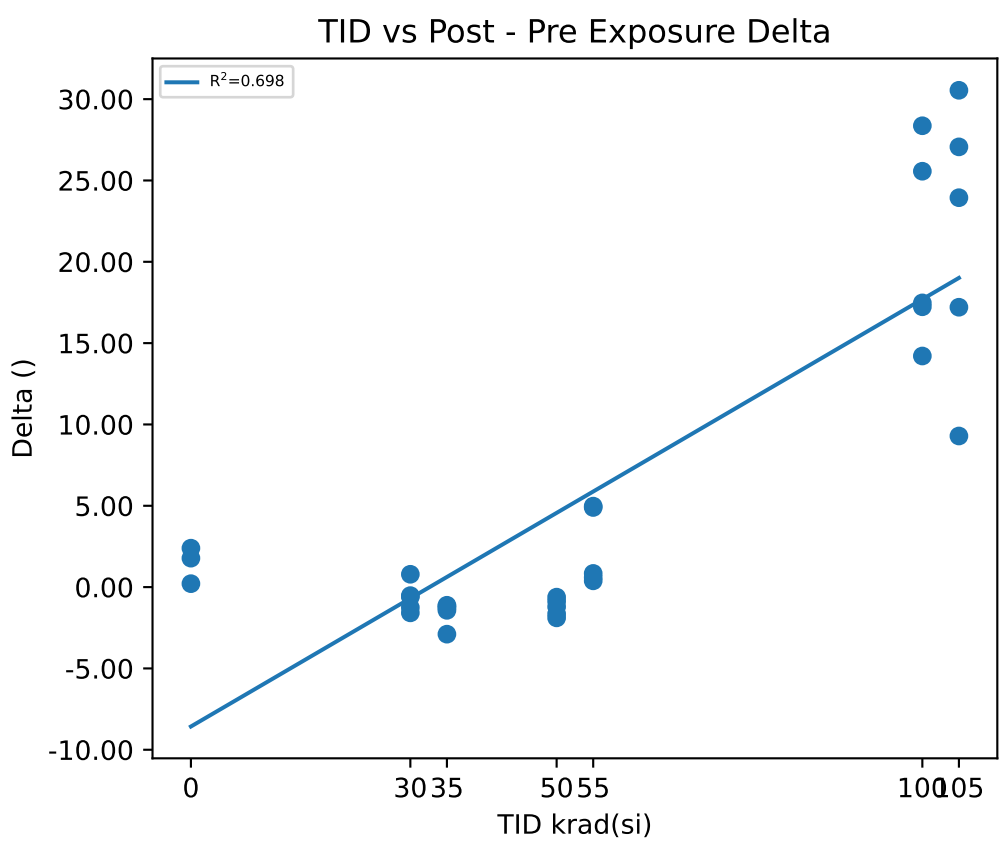
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	163.87	164	0.1352
2	0	CU2	166.11	166.26	0.1441
3	0	CU3	164.72	164.98	0.2629
11	30	Unbiased-30krad	167.37	165.82	-1.5556
12	30	Unbiased-30krad	167.96	166.22	-1.7432
13	30	Unbiased-30krad	168.19	164.72	-3.4717
14	30	Unbiased-30krad	165.92	164.1	-1.8197
15	30	Unbiased-30krad	161.43	159.27	-2.1672
16	35	Biased-30krad	165.25	164.09	-1.1588
17	35	Biased-30krad	167.03	166.52	-0.5083
18	35	Biased-30krad	162.24	161.13	-1.1069
19	35	Biased-30krad	166.84	166.01	-0.8275
20	35	Biased-30krad	164.72	163.46	-1.2558
30	50	Unbiased-50krad	165.66	163.95	-1.7173
31	50	Unbiased-50krad	166.21	165.62	-0.593
32	50	Unbiased-50krad	165.91	164.61	-1.2913
33	50	Unbiased-50krad	164.37	163.24	-1.1315
34	50	Unbiased-50krad	163.15	160.84	-2.3099
40	55	Biased-50krad	166.33	165.98	-0.3526
41	55	Biased-50krad	165.58	165.93	0.3475
42	55	Biased-50krad	163.14	163.58	0.4318
43	55	Biased-50krad	166.11	166.57	0.4531
44	55	Biased-50krad	165.2	167.9	2.6984
45	100	Unbiased-100krad	168.75	183.94	15.19
46	100	Unbiased-100krad	168.79	183.94	15.155
47	100	Unbiased-100krad	169.22	204.66	35.44
48	100	Unbiased-100krad	166.48	184.76	18.279
49	100	Unbiased-100krad	165.68	181.28	15.599
50	105	Biased-100krad	164.97	176.63	11.659
51	105	Biased-100krad	166.23	182.79	16.561
52	105	Biased-100krad	166.7	187.58	20.881
53	105	Biased-100krad	168.64	194.46	25.823
54	105	Biased-100krad	164.53	182.53	18

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	163.87	164.9	166.11	1.1324	164	165.08	166.26	1.1292	0.1352	0.18073	0.2629	0.071297
30	161.43	166.18	168.19	2.7949	159.27	164.02	166.22	2.7915	-3.4717	-2.1515	-1.5556	0.77056
35	162.24	165.22	167.03	1.9397	161.13	164.24	166.52	2.1591	-1.2558	-0.97146	-0.5083	0.30395
50	163.15	165.06	166.21	1.2773	160.84	163.65	165.62	1.7994	-2.3099	-1.4086	-0.593	0.64486
55	163.14	165.27	166.33	1.2709	163.58	165.99	167.9	1.565	-0.3526	0.71564	2.6984	1.1573
100	165.68	167.79	169.22	1.5906	181.28	187.72	204.66	9.5627	15.155	19.933	35.44	8.7651
105	164.53	166.21	168.64	1.6195	176.63	184.8	194.46	6.6529	11.659	18.585	25.823	5.2459

Device Test: 45.2 _OnDeadTime|ON_TIME/SW2/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V





Test Results (Lower Limit = 100.0, Upper Limit = 250.0 ())

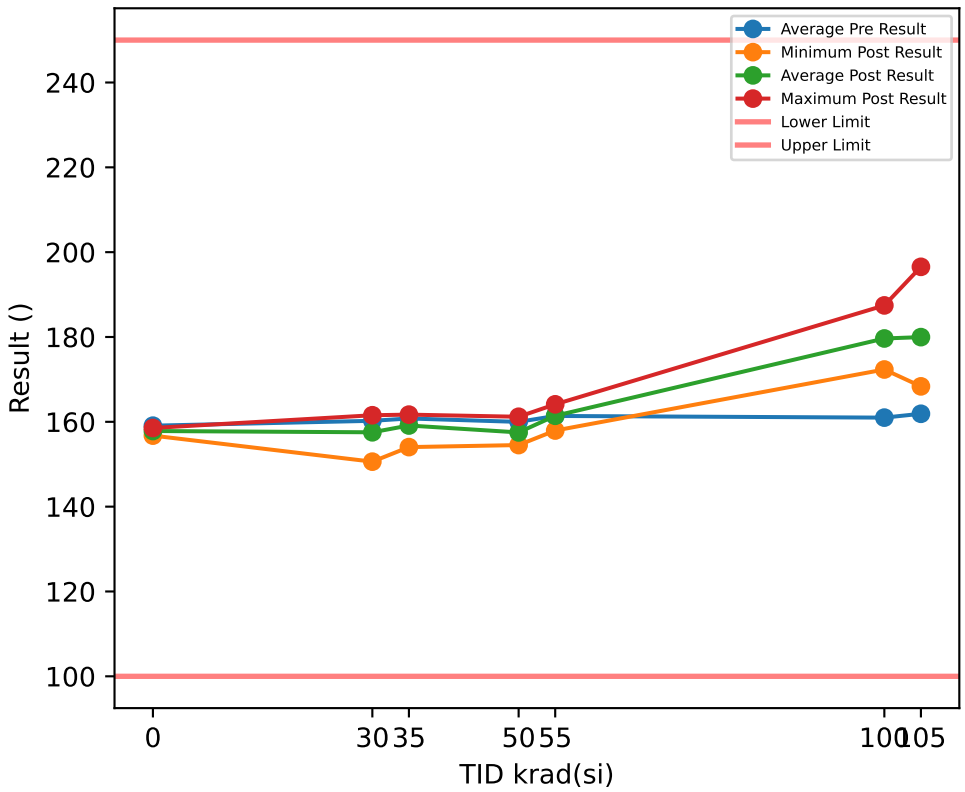
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	159.02	160.8	1.7793
2	0	CU2	159.6	162	2.3937
3	0	CU3	164.65	164.86	0.2113
11	30	Unbiased-30krad	162.72	163.51	0.7887
12	30	Unbiased-30krad	162.45	161.2	-1.2555
13	30	Unbiased-30krad	167.39	165.81	-1.583
14	30	Unbiased-30krad	164.73	164.21	-0.5231
15	30	Unbiased-30krad	152.95	152.35	-0.5978
16	35	Biased-30krad	159.77	158.47	-1.2928
17	35	Biased-30krad	168.97	166.08	-2.8936
18	35	Biased-30krad	162.44	161.27	-1.1739
19	35	Biased-30krad	161.61	160.5	-1.116
20	35	Biased-30krad	167.61	166.19	-1.4282
30	50	Unbiased-50krad	165.95	165.34	-0.6172
31	50	Unbiased-50krad	168.47	166.83	-1.6419
32	50	Unbiased-50krad	166.97	165.08	-1.8911
33	50	Unbiased-50krad	161.03	160.15	-0.8721
34	50	Unbiased-50krad	166.3	165.09	-1.2078
40	55	Biased-50krad	167.79	168.39	0.594
41	55	Biased-50krad	159.03	163.93	4.8952
42	55	Biased-50krad	159.69	160.07	0.3855
43	55	Biased-50krad	166.61	167.45	0.8413
44	55	Biased-50krad	161	165.98	4.979
45	100	Unbiased-100krad	169.23	186.47	17.235
46	100	Unbiased-100krad	161.38	186.95	25.568
47	100	Unbiased-100krad	166.28	180.49	14.209
48	100	Unbiased-100krad	168.88	186.35	17.474
49	100	Unbiased-100krad	156.47	184.84	28.365
50	105	Biased-100krad	161.69	170.98	9.2904
51	105	Biased-100krad	161.15	185.09	23.941
52	105	Biased-100krad	156.22	183.28	27.066
53	105	Biased-100krad	167.88	198.42	30.545
54	105	Biased-100krad	168.21	185.41	17.207

Test Statistics ()

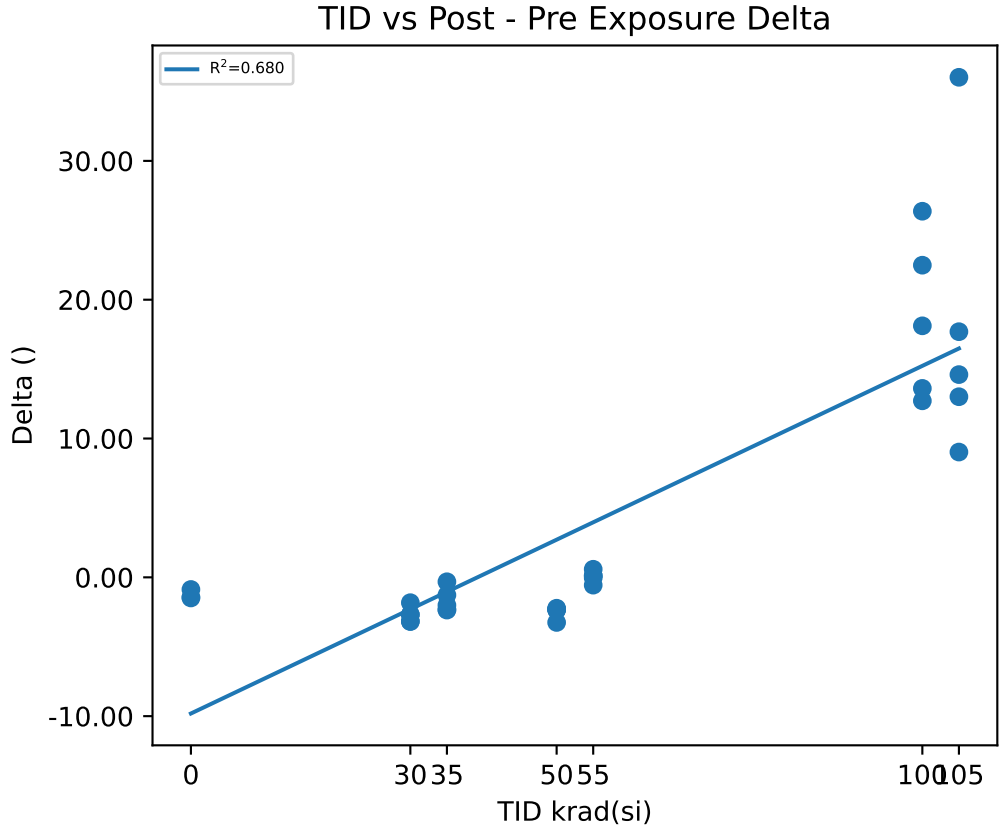
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	159.02	161.09	164.65	3.0957	160.8	162.55	164.86	2.0871	0.2113	1.4614	2.3937	1.1254
30	152.95	162.05	167.39	5.4589	152.35	161.41	165.81	5.3318	-1.583	-0.63414	0.7887	0.91167
35	159.77	164.08	168.97	3.9926	158.47	162.5	166.19	3.4679	-2.8936	-1.5809	-1.116	0.74352
50	161.03	165.74	168.47	2.8082	160.15	164.5	166.83	2.5345	-1.8911	-1.246	-0.6172	0.52667
55	159.03	162.82	167.79	4.0782	160.07	165.16	168.39	3.3048	0.3855	2.339	4.979	2.3774
100	156.47	164.45	169.23	5.4513	180.49	185.02	186.95	2.6516	14.209	20.57	28.365	6.0604
105	156.22	163.03	168.21	5.0505	170.98	184.64	198.42	9.7363	9.2904	21.61	30.545	8.4586

Device Test: 45.3 _OnDeadTime|ON_TIME/SW3/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 100.0, Upper Limit = 250.0 ())

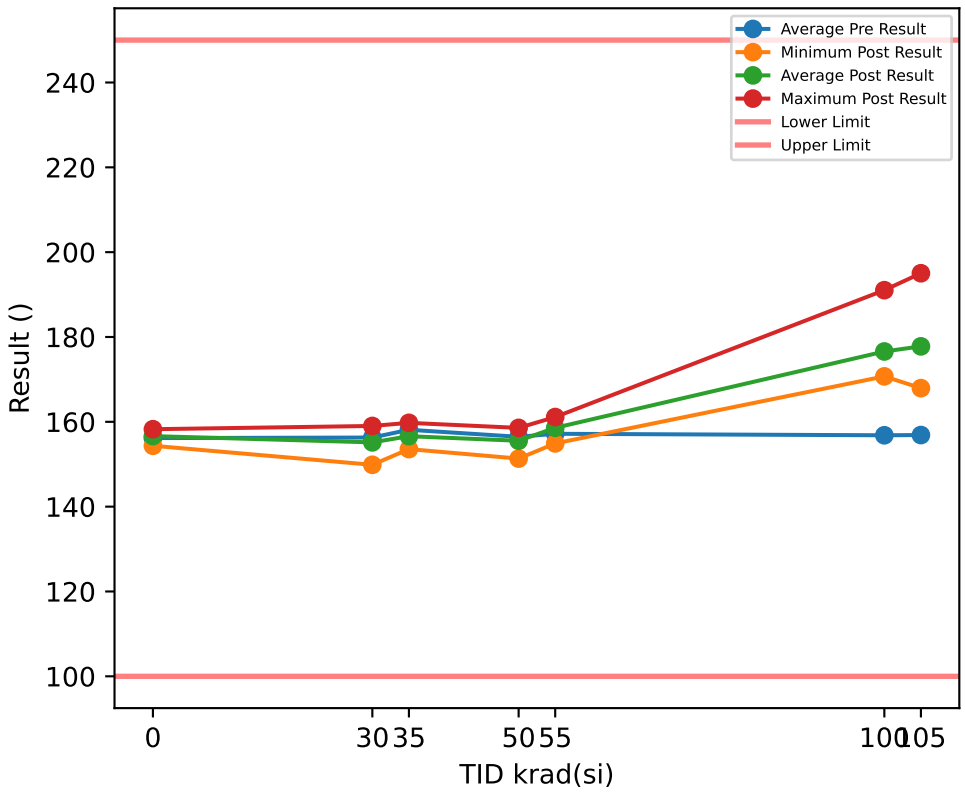
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	157.62	156.75	-0.8739
2	0	CU2	160.03	158.54	-1.4849
3	0	CU3	159.62	158.2	-1.4267
11	30	Unbiased-30krad	163.38	161.55	-1.8254
12	30	Unbiased-30krad	159.87	157.19	-2.6824
13	30	Unbiased-30krad	162.44	159.25	-3.1858
14	30	Unbiased-30krad	162.21	159.06	-3.1564
15	30	Unbiased-30krad	153.3	150.61	-2.6898
16	35	Biased-30krad	161.11	158.75	-2.3588
17	35	Biased-30krad	161.64	161.32	-0.3185
18	35	Biased-30krad	156.36	154.04	-2.3193
19	35	Biased-30krad	161.12	159.85	-1.2752
20	35	Biased-30krad	163.7	161.7	-2.0074
30	50	Unbiased-50krad	158.5	156.15	-2.35
31	50	Unbiased-50krad	161.26	158.97	-2.2898
32	50	Unbiased-50krad	159	156.67	-2.3262
33	50	Unbiased-50krad	163.42	161.19	-2.2246
34	50	Unbiased-50krad	157.77	154.52	-3.2496
40	55	Biased-50krad	164.16	164.13	-0.0377
41	55	Biased-50krad	161.14	160.58	-0.5627
42	55	Biased-50krad	157.82	157.95	0.1228
43	55	Biased-50krad	161.28	161.87	0.5823
44	55	Biased-50krad	162.49	162.62	0.124
45	100	Unbiased-100krad	161.76	175.37	13.611
46	100	Unbiased-100krad	160.52	178.64	18.119
47	100	Unbiased-100krad	161.07	187.45	26.374
48	100	Unbiased-100krad	161.98	184.46	22.486
49	100	Unbiased-100krad	159.62	172.34	12.716
50	105	Biased-100krad	159.33	168.36	9.0254
51	105	Biased-100krad	162.28	175.29	13.012
52	105	Biased-100krad	160.52	196.54	36.023
53	105	Biased-100krad	163.48	181.17	17.696
54	105	Biased-100krad	163.87	178.47	14.606

Test Statistics ()

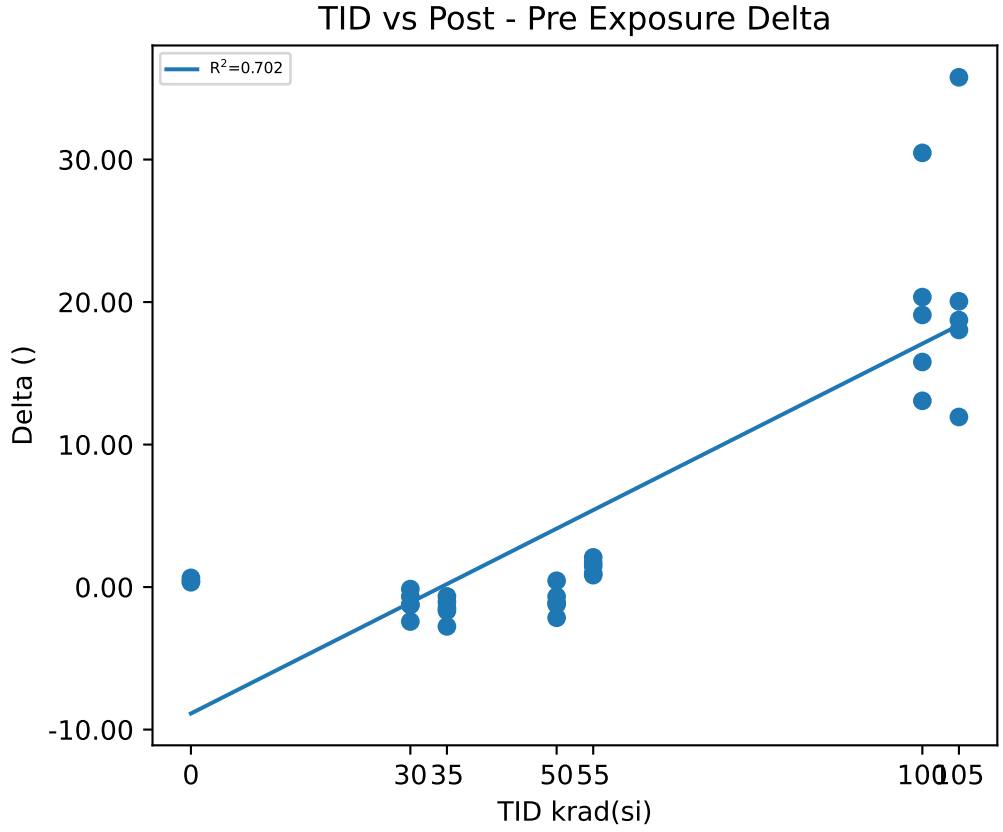
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	157.62	159.09	160.03	1.2899	156.75	157.83	158.54	0.95382	-1.4849	-1.2618	-0.8739	0.33722
30	153.3	160.24	163.38	4.0893	150.61	157.53	161.55	4.1681	-3.1858	-2.708	-1.8254	0.54985
35	156.36	160.79	163.7	2.6957	154.04	159.13	161.7	3.0808	-2.3588	-1.6558	-0.3185	0.86477
50	157.77	159.99	163.42	2.3189	154.52	157.5	161.19	2.6077	-3.2496	-2.488	-2.2246	0.42835
55	157.82	161.38	164.16	2.3288	157.95	161.43	164.13	2.3302	-0.5627	0.04574	0.5823	0.41144
100	159.62	160.99	161.98	0.95829	172.34	179.65	187.45	6.2599	12.716	18.661	26.374	5.8149
105	159.33	161.9	163.87	1.936	168.36	179.97	196.54	10.428	9.0254	18.072	36.023	10.51

Device Test: 45.4 _OnDeadTime|ON_TIME/SW4/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 100.0, Upper Limit = 250.0 ())

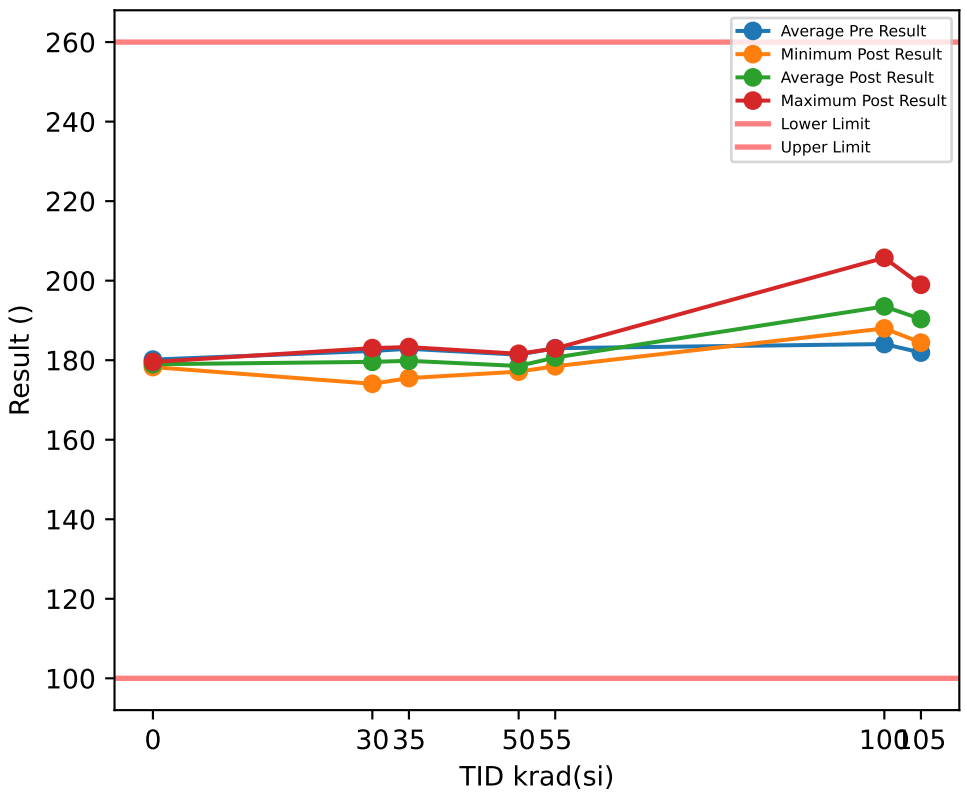
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	156.95	157.28	0.336
2	0	CU2	157.61	158.26	0.6463
3	0	CU3	153.93	154.35	0.4213
11	30	Unbiased-30krad	159.69	159.03	-0.664
12	30	Unbiased-30krad	155.51	154.26	-1.2518
13	30	Unbiased-30krad	160.06	157.64	-2.4187
14	30	Unbiased-30krad	156.22	154.98	-1.2366
15	30	Unbiased-30krad	150.01	149.87	-0.1404
16	35	Biased-30krad	156.36	154.7	-1.6639
17	35	Biased-30krad	159.08	158.42	-0.6555
18	35	Biased-30krad	156.33	153.57	-2.7607
19	35	Biased-30krad	157.63	156.59	-1.0422
20	35	Biased-30krad	161.22	159.76	-1.463
30	50	Unbiased-50krad	155.67	156.12	0.4441
31	50	Unbiased-50krad	160.73	158.57	-2.1562
32	50	Unbiased-50krad	157.83	156.74	-1.0911
33	50	Unbiased-50krad	156.12	154.91	-1.2148
34	50	Unbiased-50krad	152	151.33	-0.6688
40	55	Biased-50krad	160.29	161.13	0.836
41	55	Biased-50krad	153.94	154.91	0.9658
42	55	Biased-50krad	154.93	156.64	1.7047
43	55	Biased-50krad	157.41	159.5	2.0847
44	55	Biased-50krad	159.31	160.77	1.4636
45	100	Unbiased-100krad	158.51	171.59	13.071
46	100	Unbiased-100krad	155.91	175.01	19.096
47	100	Unbiased-100krad	160.57	191.03	30.469
48	100	Unbiased-100krad	154.23	174.57	20.348
49	100	Unbiased-100krad	154.92	170.71	15.794
50	105	Biased-100krad	156	167.94	11.936
51	105	Biased-100krad	157.97	178.02	20.054
52	105	Biased-100krad	155.06	173.79	18.738
53	105	Biased-100krad	159.26	195.03	35.773
54	105	Biased-100krad	156.13	174.17	18.042

Test Statistics ()

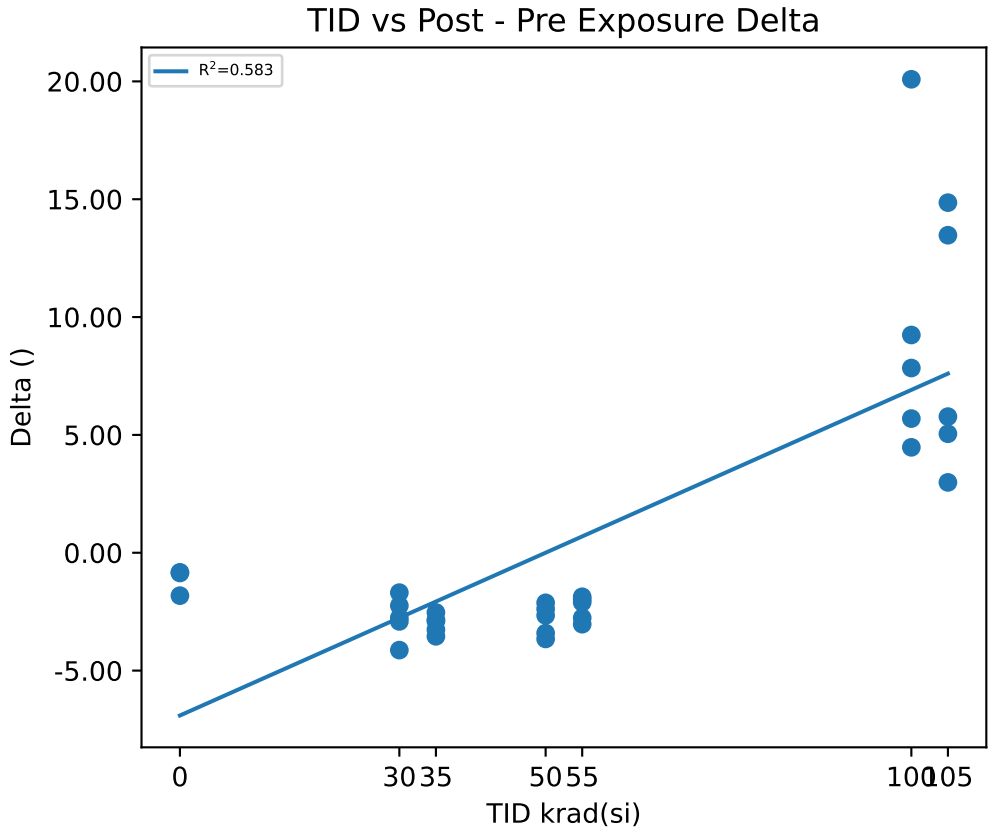
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	153.93	156.16	157.61	1.9602	154.35	156.63	158.26	2.0315	0.336	0.46787	0.6463	0.16031
30	150.01	156.3	160.06	4.0577	149.87	155.15	159.03	3.5343	-2.4187	-1.1423	-0.1404	0.84892
35	156.33	158.12	161.22	2.0655	153.57	156.61	159.76	2.5548	-2.7607	-1.5171	-0.6555	0.7967
50	152	156.47	160.73	3.1893	151.33	155.53	158.57	2.6952	-2.1562	-0.93736	0.4441	0.94429
55	153.94	157.18	160.29	2.7312	154.91	158.59	161.13	2.7124	0.836	1.411	2.0847	0.51762
100	154.23	156.83	160.57	2.6489	170.71	176.58	191.03	8.2887	13.071	19.756	30.469	6.6324
105	155.06	156.88	159.26	1.6952	167.94	177.79	195.03	10.287	11.936	20.909	35.773	8.8756

Device Test: 46.1 _OnDeadTime|ON_TIME/SW1/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



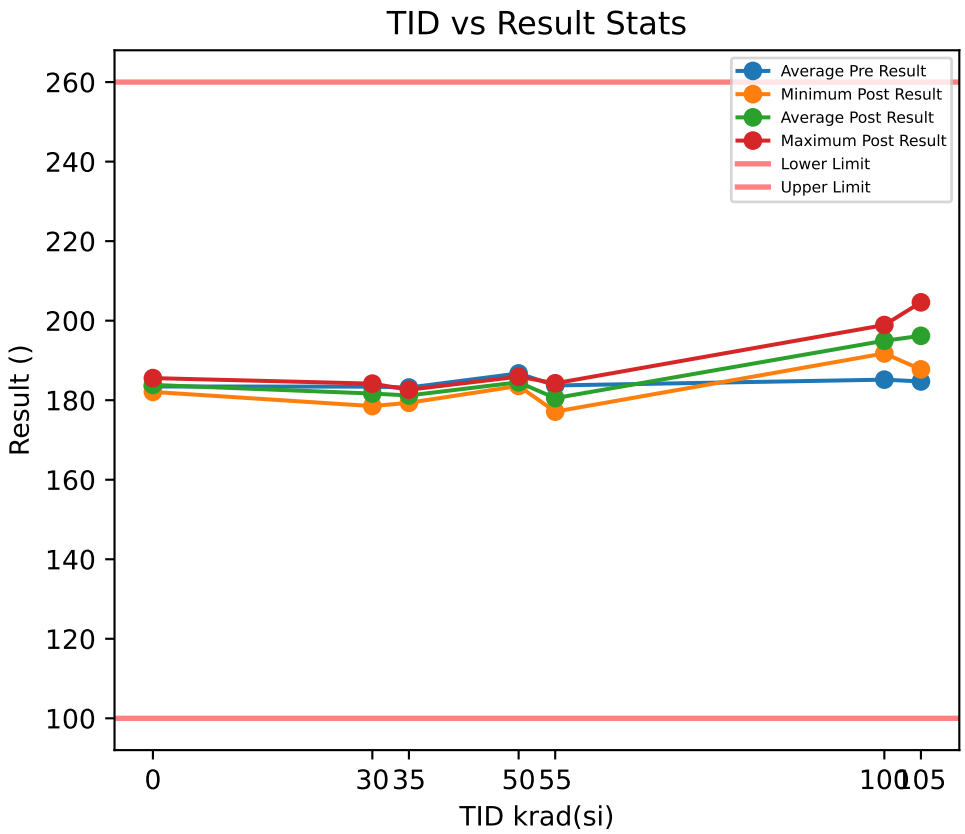
Test Results (Lower Limit = 100.0, Upper Limit = 260.0 ())

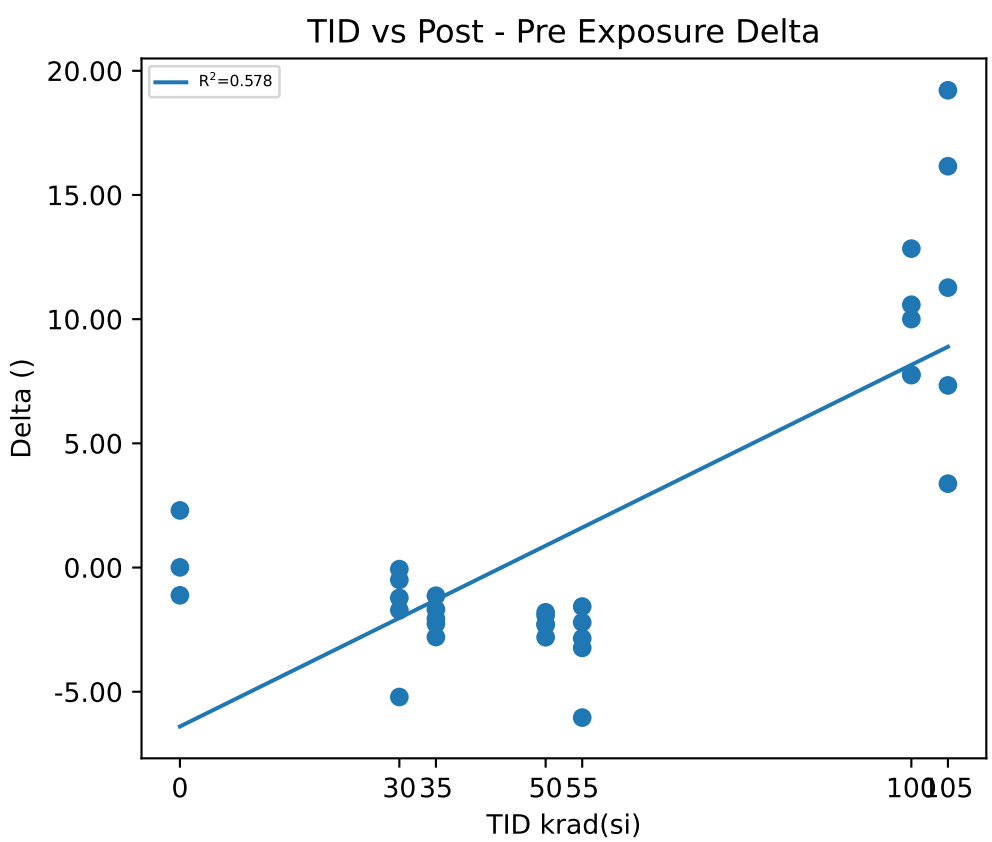
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	179.95	179.12	-0.8307
2	0	CU2	181.37	179.55	-1.8206
3	0	CU3	179.12	178.27	-0.858
11	30	Unbiased-30krad	184.74	183.05	-1.692
12	30	Unbiased-30krad	184.56	181.65	-2.9128
13	30	Unbiased-30krad	182.9	178.77	-4.1306
14	30	Unbiased-30krad	183.14	180.38	-2.758
15	30	Unbiased-30krad	176.31	174.07	-2.2427
16	35	Biased-30krad	183.1	179.55	-3.5459
17	35	Biased-30krad	186.21	183.3	-2.9023
18	35	Biased-30krad	178.76	175.5	-3.2606
19	35	Biased-30krad	183.89	181.36	-2.5346
20	35	Biased-30krad	182.36	179.52	-2.8463
30	50	Unbiased-50krad	180.87	177.47	-3.409
31	50	Unbiased-50krad	184	181.61	-2.3865
32	50	Unbiased-50krad	181.67	179.01	-2.6592
33	50	Unbiased-50krad	179.63	177.51	-2.1243
34	50	Unbiased-50krad	180.78	177.12	-3.6571
40	55	Biased-50krad	184.65	182.67	-1.9828
41	55	Biased-50krad	181.72	178.95	-2.7624
42	55	Biased-50krad	180.58	178.47	-2.106
43	55	Biased-50krad	183.35	180.31	-3.0311
44	55	Biased-50krad	184.82	182.95	-1.8683
45	100	Unbiased-100krad	186.05	190.52	4.4733
46	100	Unbiased-100krad	184.2	192.04	7.8381
47	100	Unbiased-100krad	185.65	205.74	20.089
48	100	Unbiased-100krad	182.07	191.31	9.2397
49	100	Unbiased-100krad	182.3	188	5.6929
50	105	Biased-100krad	181.44	184.42	2.9853
51	105	Biased-100krad	180.73	186.5	5.7764
52	105	Biased-100krad	181.36	194.84	13.473
53	105	Biased-100krad	184.11	198.97	14.855
54	105	Biased-100krad	181.92	186.97	5.0487

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	179.12	180.15	181.37	1.1376	178.27	178.98	179.55	0.65478	-1.8206	-1.1698	-0.8307	0.5638
30	176.31	182.33	184.74	3.4652	174.07	179.58	183.05	3.4646	-4.1306	-2.7472	-1.692	0.90957
35	178.76	182.86	186.21	2.7102	175.5	179.85	183.3	2.8868	-3.5459	-3.0179	-2.5346	0.39182
50	179.63	181.39	184	1.6286	177.12	178.55	181.61	1.8632	-3.6571	-2.8472	-2.1243	0.65987
55	180.58	183.02	184.82	1.8475	178.47	180.67	182.95	2.0666	-3.0311	-2.3501	-1.8683	0.51487
100	182.07	184.06	186.05	1.8402	188	193.52	205.74	6.9988	4.4733	9.4666	20.089	6.2192
105	180.73	181.91	184.11	1.3022	184.42	190.34	198.97	6.2402	2.9853	8.4278	14.855	5.3581

Device Test: 46.2 _OnDeadTime|ON_TIME/SW2/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V





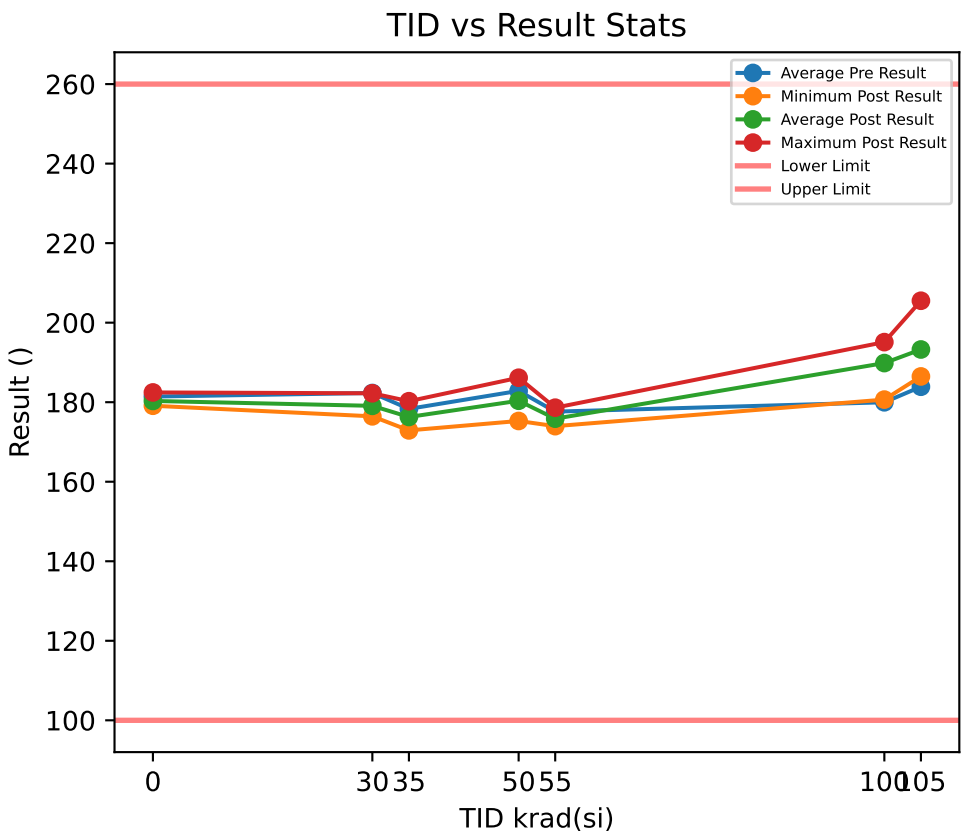
Test Results (Lower Limit = 100.0, Upper Limit = 260.0 ())

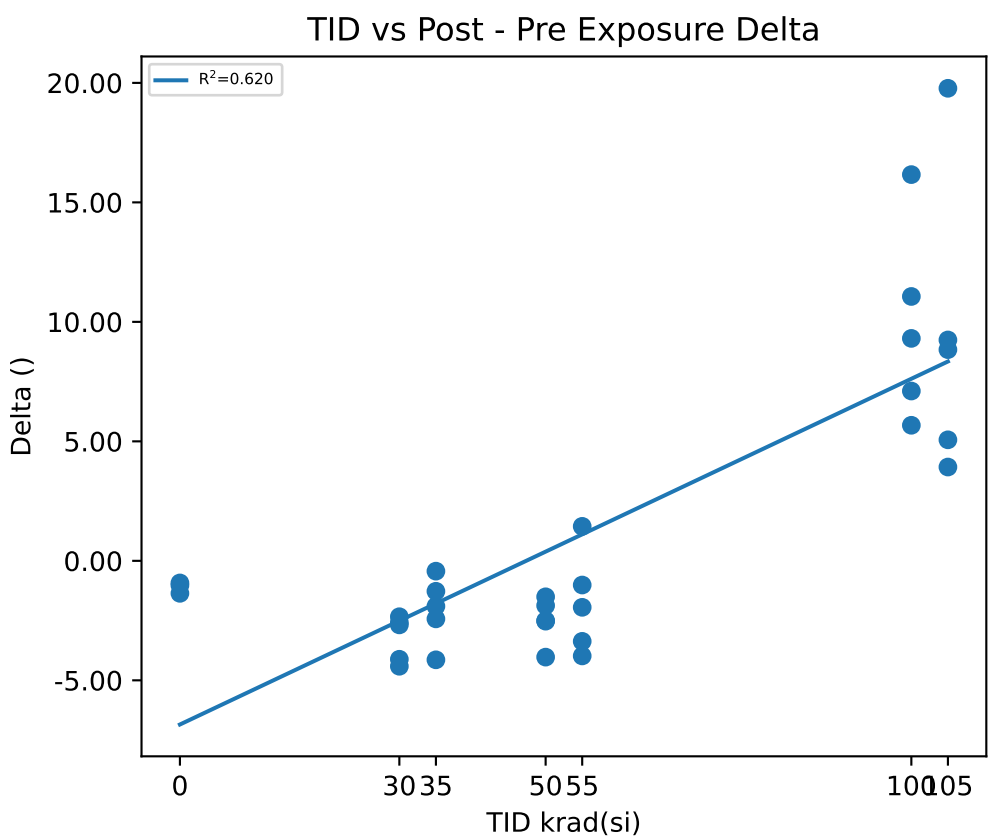
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	183.26	185.56	2.299
2	0	CU2	183.2	182.08	-1.1181
3	0	CU3	183.89	183.9	0.0073
11	30	Unbiased-30krad	186.08	180.86	-5.2114
12	30	Unbiased-30krad	182.61	181.39	-1.2189
13	30	Unbiased-30krad	185.88	184.17	-1.7163
14	30	Unbiased-30krad	183.9	183.41	-0.4969
15	30	Unbiased-30krad	178.58	178.52	-0.0625
16	35	Biased-30krad	183.92	181.12	-2.7982
17	35	Biased-30krad	183.76	182.63	-1.1346
18	35	Biased-30krad	182.81	180.55	-2.2613
19	35	Biased-30krad	181.03	179.34	-1.6887
20	35	Biased-30krad	184.38	182.33	-2.0573
30	50	Unbiased-50krad	186.8	184.49	-2.3117
31	50	Unbiased-50krad	187.72	185.92	-1.8021
32	50	Unbiased-50krad	186.44	184.16	-2.2784
33	50	Unbiased-50krad	186.39	183.58	-2.8062
34	50	Unbiased-50krad	186.32	184.4	-1.9237
40	55	Biased-50krad	186.99	183.75	-3.2349
41	55	Biased-50krad	182.11	179.9	-2.2071
42	55	Biased-50krad	183.63	177.59	-6.0411
43	55	Biased-50krad	185.82	184.25	-1.5697
44	55	Biased-50krad	179.97	177.12	-2.8496
45	100	Unbiased-100krad	187.11	194.86	7.746
46	100	Unbiased-100krad	188.9	198.9	10.003
47	100	Unbiased-100krad	184.57	192.34	7.772
48	100	Unbiased-100krad	186.32	196.9	10.581
49	100	Unbiased-100krad	178.93	191.77	12.84
50	105	Biased-100krad	184.37	187.75	3.3769
51	105	Biased-100krad	182.91	194.18	11.27
52	105	Biased-100krad	182.82	198.97	16.157
53	105	Biased-100krad	185.4	204.61	19.215
54	105	Biased-100krad	188.08	195.41	7.3328

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	183.2	183.45	183.89	0.3831	182.08	183.85	185.56	1.7369	-1.1181	0.39607	2.299	1.7414
30	178.58	183.41	186.08	3.0574	178.52	181.67	184.17	2.2292	-5.2114	-1.7412	-0.0625	2.0422
35	181.03	183.18	184.38	1.3299	179.34	181.19	182.63	1.3402	-2.7982	-1.988	-1.1346	0.62326
50	186.32	186.73	187.72	0.58221	183.58	184.51	185.92	0.86335	-2.8062	-2.2244	-1.8021	0.393
55	179.97	183.7	186.99	2.8184	177.12	180.52	184.25	3.3509	-6.0411	-3.1805	-1.5697	1.7203
100	178.93	185.17	188.9	3.8192	191.77	194.95	198.9	3.0154	7.746	9.7884	12.84	2.1345
105	182.82	184.71	188.08	2.1657	187.75	196.18	204.61	6.2162	3.3769	11.47	19.215	6.4149

Device Test: 46.3 _OnDeadTime|ON_TIME/SW3/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V





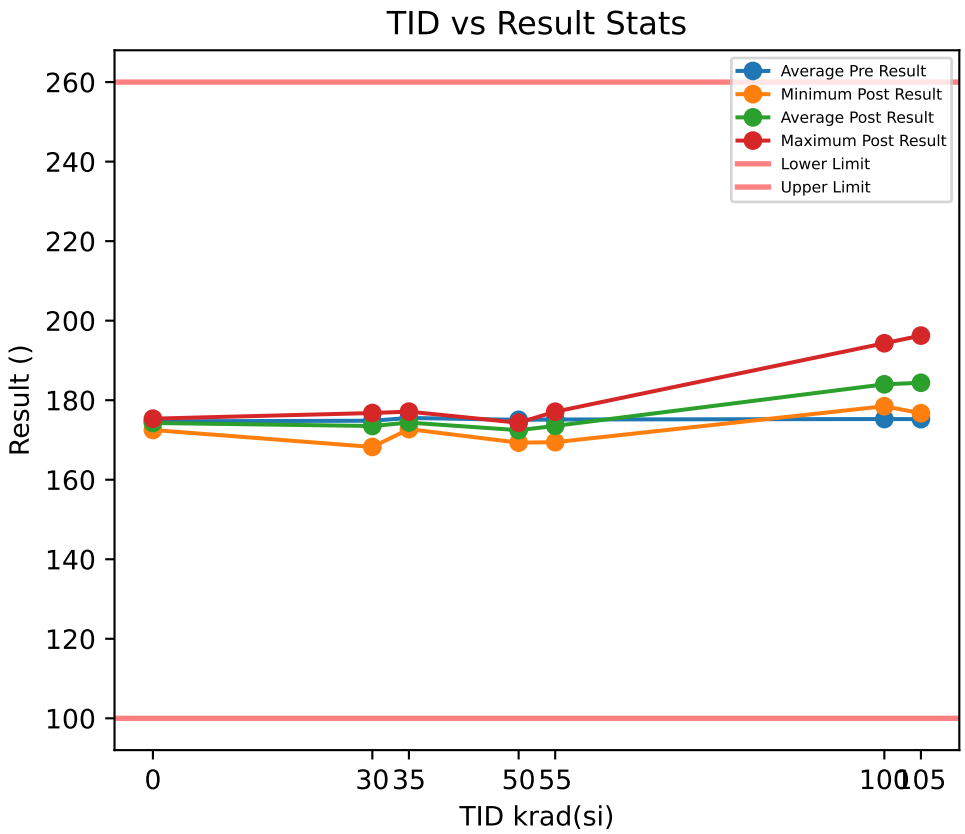
Test Results (Lower Limit = 100.0, Upper Limit = 260.0 ())

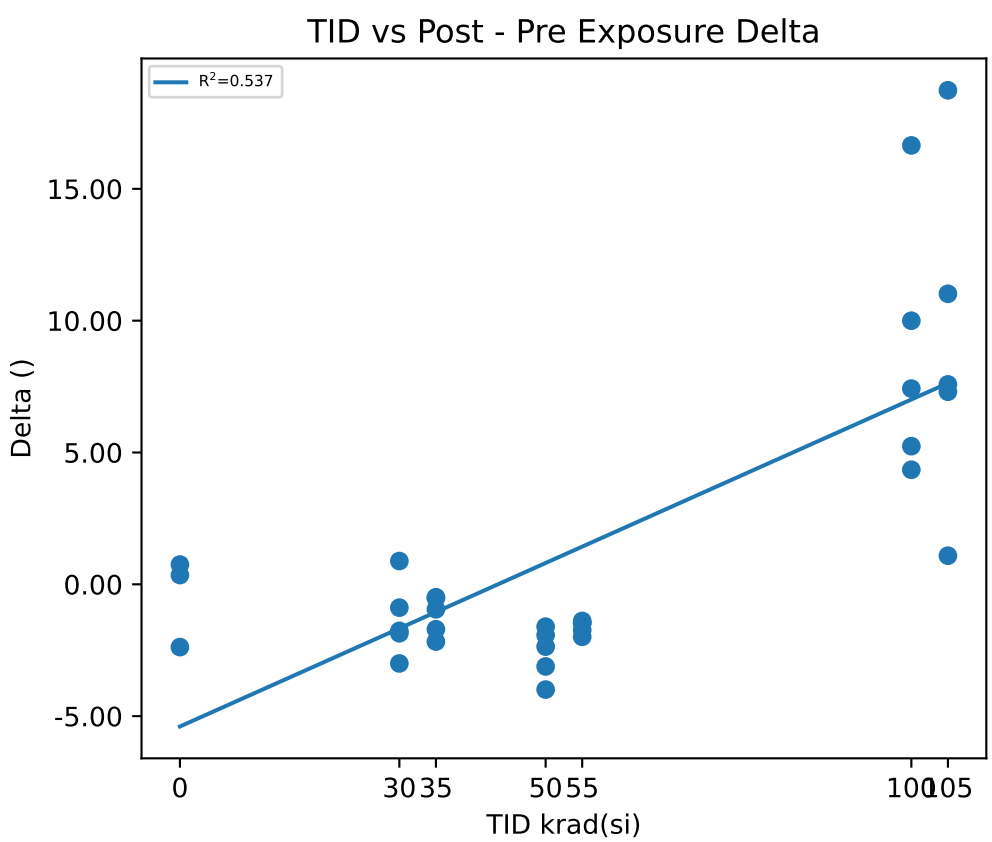
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	183.38	182.45	-0.9249
2	0	CU2	180.13	179.11	-1.0236
3	0	CU3	180.75	179.39	-1.3597
11	30	Unbiased-30krad	180.56	176.45	-4.1183
12	30	Unbiased-30krad	181.99	177.57	-4.4115
13	30	Unbiased-30krad	184.19	181.85	-2.339
14	30	Unbiased-30krad	184.82	182.24	-2.5799
15	30	Unbiased-30krad	179.98	177.3	-2.6802
16	35	Biased-30krad	180.99	179.09	-1.8995
17	35	Biased-30krad	175.42	172.99	-2.4285
18	35	Biased-30krad	180.68	180.25	-0.4319
19	35	Biased-30krad	177.46	176.19	-1.2734
20	35	Biased-30krad	177.05	172.91	-4.1416
30	50	Unbiased-50krad	182.75	180.88	-1.8712
31	50	Unbiased-50krad	177.8	175.28	-2.5241
32	50	Unbiased-50krad	181.72	180.21	-1.5052
33	50	Unbiased-50krad	188.65	186.15	-2.5015
34	50	Unbiased-50krad	183.33	179.31	-4.029
40	55	Biased-50krad	179.69	177.75	-1.945
41	55	Biased-50krad	177.17	178.62	1.4434
42	55	Biased-50krad	178.37	174.39	-3.9787
43	55	Biased-50krad	174.99	173.98	-1.0118
44	55	Biased-50krad	177.91	174.54	-3.3687
45	100	Unbiased-100krad	174.98	180.65	5.6726
46	100	Unbiased-100krad	181.88	192.95	11.063
47	100	Unbiased-100krad	178.95	195.11	16.162
48	100	Unbiased-100krad	183.41	192.71	9.3085
49	100	Unbiased-100krad	180.68	187.78	7.106
50	105	Biased-100krad	182.55	186.48	3.9255
51	105	Biased-100krad	183.47	188.54	5.0642
52	105	Biased-100krad	185.74	205.51	19.774
53	105	Biased-100krad	183.34	192.18	8.8383
54	105	Biased-100krad	184.34	193.58	9.243

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	180.13	181.42	183.38	1.725	179.11	180.32	182.45	1.8565	-1.3597	-1.1027	-0.9249	0.22795
30	179.98	182.31	184.82	2.1461	176.45	179.08	182.24	2.7413	-4.4115	-3.2258	-2.339	0.96225
35	175.42	178.32	180.99	2.4204	172.91	176.29	180.25	3.3837	-4.1416	-2.035	-0.4319	1.3929
50	177.8	182.85	188.65	3.8946	175.28	180.37	186.15	3.8977	-4.029	-2.4862	-1.5052	0.96469
55	174.99	177.63	179.69	1.7377	173.98	175.86	178.62	2.157	-3.9787	-1.7722	1.4434	2.1428
100	174.98	179.98	183.41	3.2364	180.65	189.84	195.11	5.7944	5.6726	9.8625	16.162	4.0802
105	182.55	183.89	185.74	1.2132	186.48	193.26	205.51	7.4114	3.9255	9.369	19.774	6.2595

Device Test: 46.4 _OnDeadTime|ON_TIME/SW4/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V





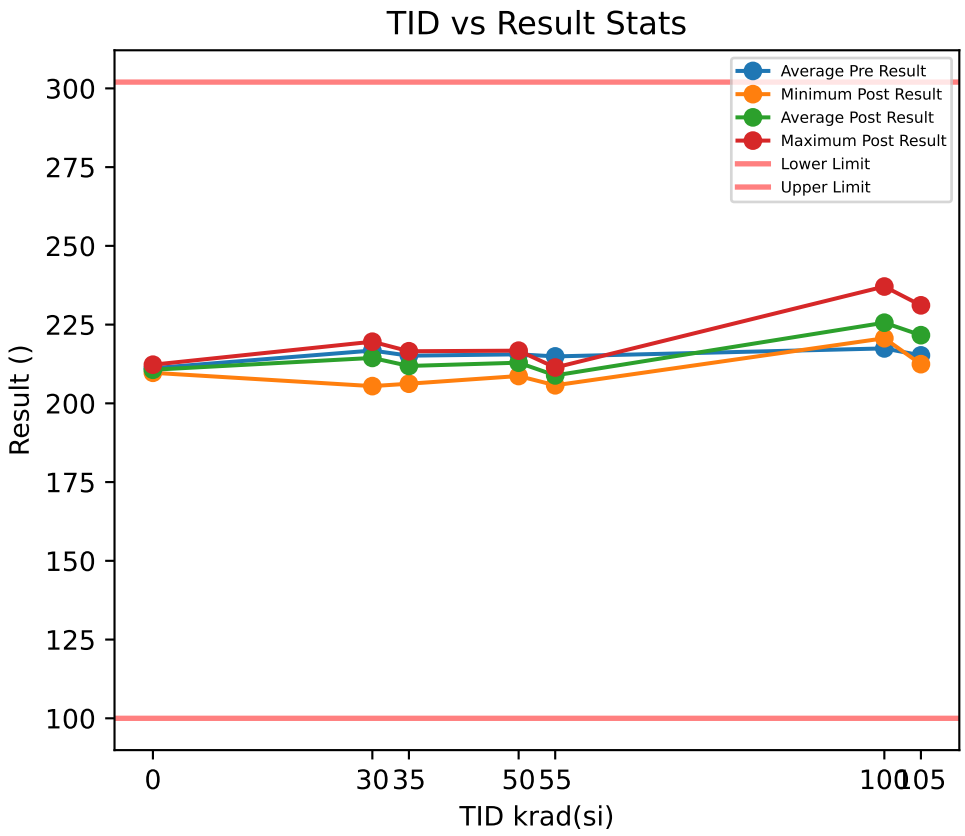
Test Results (Lower Limit = 100.0, Upper Limit = 260.0 ())

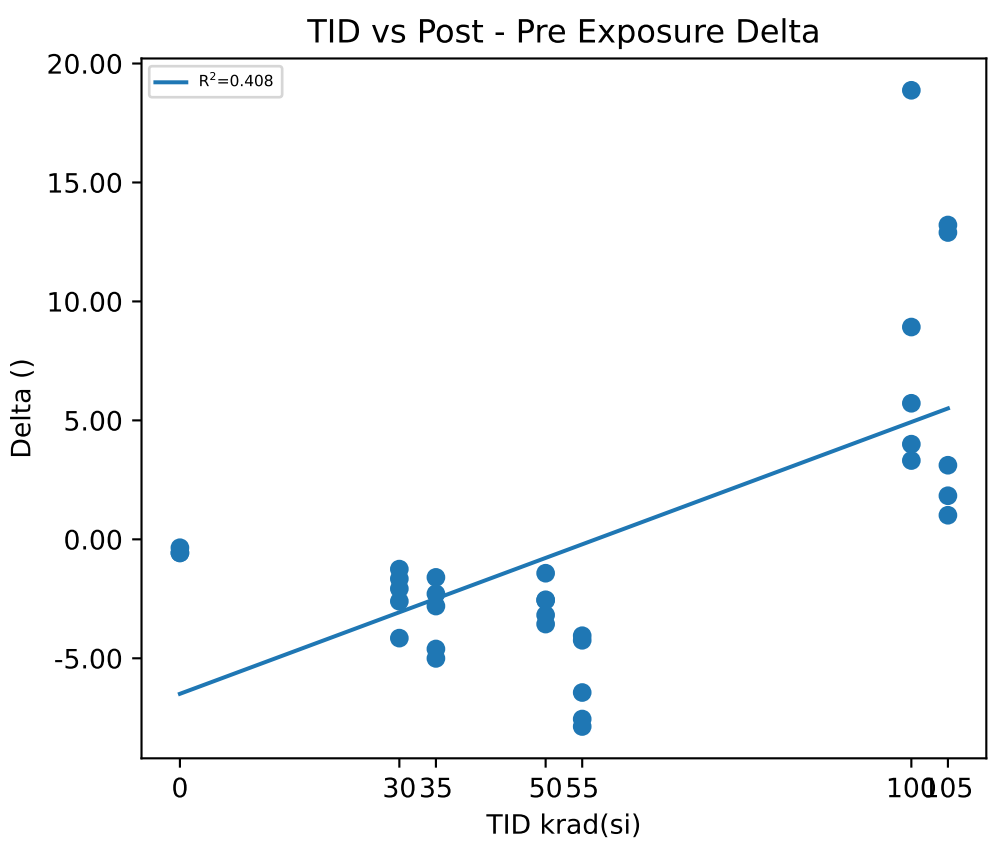
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	174.61	175.35	0.7491
2	0	CU2	177.32	174.94	-2.3819
3	0	CU3	172.16	172.51	0.3519
11	30	Unbiased-30krad	178.63	176.77	-1.8571
12	30	Unbiased-30krad	174.95	173.18	-1.7665
13	30	Unbiased-30krad	178.54	175.54	-3.001
14	30	Unbiased-30krad	174.71	173.83	-0.8849
15	30	Unbiased-30krad	167.35	168.24	0.8834
16	35	Biased-30krad	174.89	172.72	-2.1723
17	35	Biased-30krad	176.57	174.86	-1.7042
18	35	Biased-30krad	173.98	173.03	-0.9475
19	35	Biased-30krad	174.59	174.1	-0.4905
20	35	Biased-30krad	177.65	177.13	-0.5196
30	50	Unbiased-50krad	176.26	174.33	-1.9254
31	50	Unbiased-50krad	177.52	173.53	-3.9923
32	50	Unbiased-50krad	176.06	172.95	-3.1152
33	50	Unbiased-50krad	173.79	172.18	-1.6077
34	50	Unbiased-50krad	171.69	169.33	-2.3641
40	55	Biased-50krad	178.58	177.11	-1.4733
41	55	Biased-50krad	170.83	169.44	-1.3892
42	55	Biased-50krad	172.92	171.45	-1.4628
43	55	Biased-50krad	175.55	173.81	-1.7358
44	55	Biased-50krad	177.86	175.87	-1.9903
45	100	Unbiased-100krad	177.43	181.78	4.3449
46	100	Unbiased-100krad	176.35	183.78	7.4236
47	100	Unbiased-100krad	177.67	194.32	16.648
48	100	Unbiased-100krad	171.6	181.6	9.9982
49	100	Unbiased-100krad	173.24	178.48	5.2393
50	105	Biased-100krad	175.64	176.72	1.0853
51	105	Biased-100krad	174.8	182.1	7.3054
52	105	Biased-100krad	174.38	185.4	11.02
53	105	Biased-100krad	177.51	196.24	18.738
54	105	Biased-100krad	173.86	181.45	7.5824

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	172.16	174.69	177.32	2.5826	172.51	174.27	175.35	1.5371	-2.3819	-0.42697	0.7491	1.7046
30	167.35	174.84	178.63	4.5864	168.24	173.51	176.77	3.2704	-3.001	-1.3252	0.8834	1.4455
35	173.98	175.54	177.65	1.5201	172.72	174.37	177.13	1.7625	-2.1723	-1.1668	-0.4905	0.74568
50	171.69	175.06	177.52	2.3164	169.33	172.46	174.33	1.922	-3.9923	-2.6009	-1.6077	0.96168
55	170.83	175.15	178.58	3.2763	169.44	173.54	177.11	3.1384	-1.9903	-1.6103	-1.3892	0.24978
100	171.6	175.26	177.67	2.7013	178.48	183.99	194.32	6.0771	4.3449	8.7309	16.648	4.9353
105	173.86	175.24	177.51	1.4253	176.72	184.38	196.24	7.3186	1.0853	9.1462	18.738	6.4484

Device Test: 47.1 _OnDeadTime|ON_TIME/SW1/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V





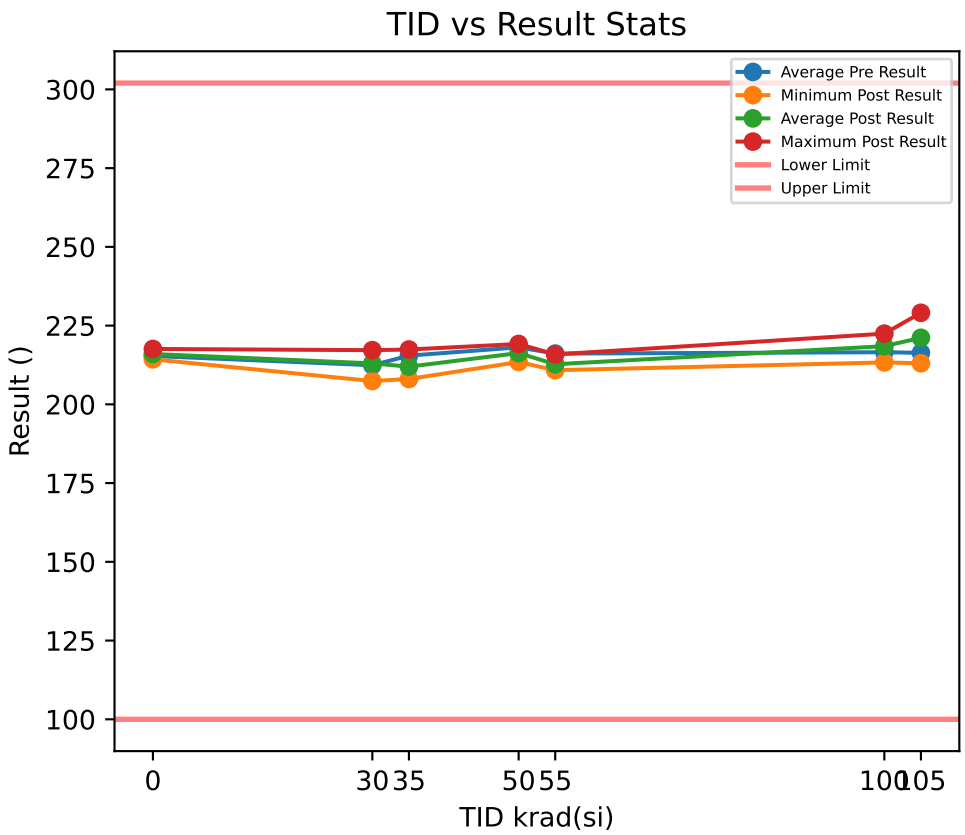
Test Results (Lower Limit = 100.0, Upper Limit = 302.0 ())

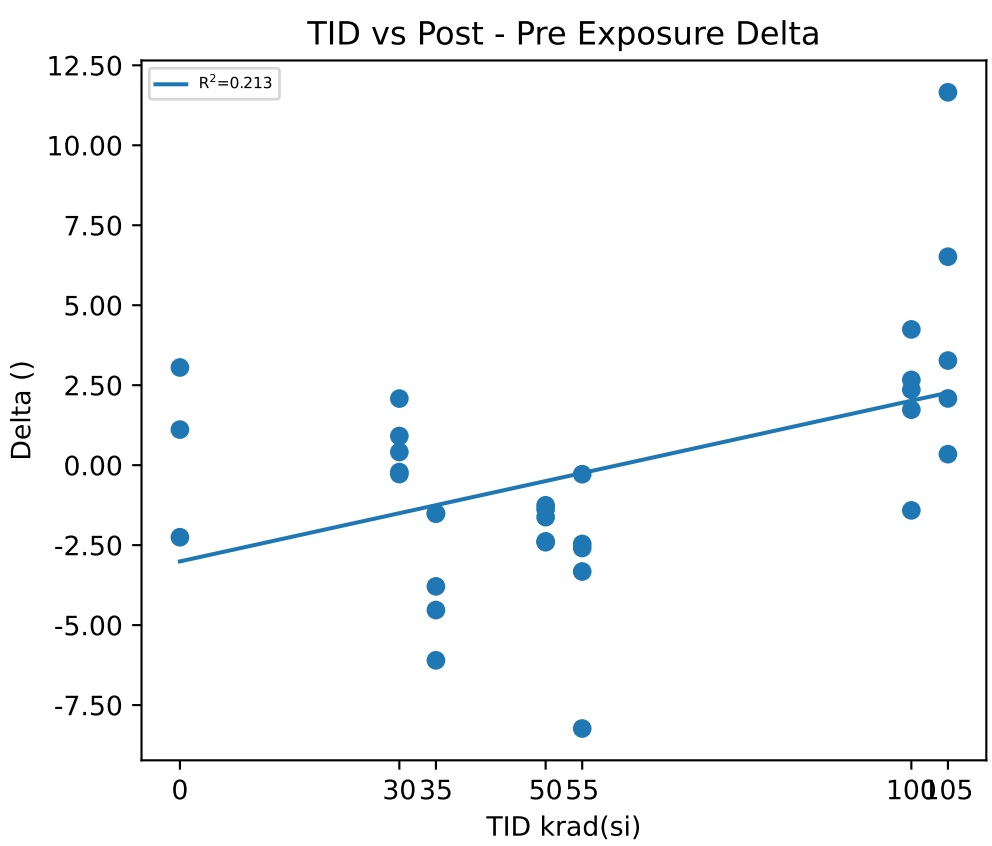
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	212.84	212.27	-0.5696
2	0	CU2	210.38	210.03	-0.3522
3	0	CU3	210.27	209.7	-0.57
11	30	Unbiased-30krad	219.39	217.73	-1.6577
12	30	Unbiased-30krad	222.17	219.57	-2.6018
13	30	Unbiased-30krad	216.08	214.83	-1.2507
14	30	Unbiased-30krad	216.59	214.51	-2.0745
15	30	Unbiased-30krad	209.62	205.47	-4.1521
16	35	Biased-30krad	218.14	216.54	-1.5989
17	35	Biased-30krad	216.97	212.36	-4.6081
18	35	Biased-30krad	212.92	210.63	-2.2887
19	35	Biased-30krad	216.39	213.59	-2.8046
20	35	Biased-30krad	211.24	206.23	-5.0046
30	50	Unbiased-50krad	212.24	208.68	-3.5617
31	50	Unbiased-50krad	215.09	213.66	-1.4239
32	50	Unbiased-50krad	213.28	210.72	-2.5618
33	50	Unbiased-50krad	219.91	216.73	-3.182
34	50	Unbiased-50krad	217.3	214.76	-2.5406
40	55	Biased-50krad	215.29	211.24	-4.0507
41	55	Biased-50krad	216.74	208.87	-7.8669
42	55	Biased-50krad	214.7	207.15	-7.5527
43	55	Biased-50krad	212.17	205.73	-6.4381
44	55	Biased-50krad	215.62	211.37	-4.2433
45	100	Unbiased-100krad	217.73	221.04	3.3125
46	100	Unbiased-100krad	218.11	227.04	8.9238
47	100	Unbiased-100krad	218.22	237.09	18.875
48	100	Unbiased-100krad	216.47	222.19	5.7195
49	100	Unbiased-100krad	216.67	220.67	4.0007
50	105	Biased-100krad	218.27	219.28	1.0128
51	105	Biased-100krad	210.61	212.44	1.8328
52	105	Biased-100krad	217.91	231.12	13.212
53	105	Biased-100krad	216.81	229.7	12.897
54	105	Biased-100krad	212.54	215.66	3.115

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	210.27	211.16	212.84	1.4527	209.7	210.67	212.27	1.3984	-0.57	-0.49727	-0.3522	0.12563
30	209.62	216.77	222.17	4.6813	205.47	214.42	219.57	5.4262	-4.1521	-2.3474	-1.2507	1.1263
35	211.24	215.13	218.14	2.9196	206.23	211.87	216.54	3.8187	-5.0046	-3.261	-1.5989	1.4808
50	212.24	215.56	219.91	3.0984	208.68	212.91	216.73	3.2128	-3.5617	-2.654	-1.4239	0.81197
55	212.17	214.9	216.74	1.6987	205.73	208.87	211.37	2.4846	-7.8669	-6.0303	-4.0507	1.8006
100	216.47	217.44	218.22	0.81674	220.67	225.61	237.09	6.907	3.3125	8.1663	18.875	6.3668
105	210.61	215.23	218.27	3.4446	212.44	221.64	231.12	8.3796	1.0128	6.414	13.212	6.1092

Device Test: 47.2 _OnDeadTime|ON_TIME/SW2/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V





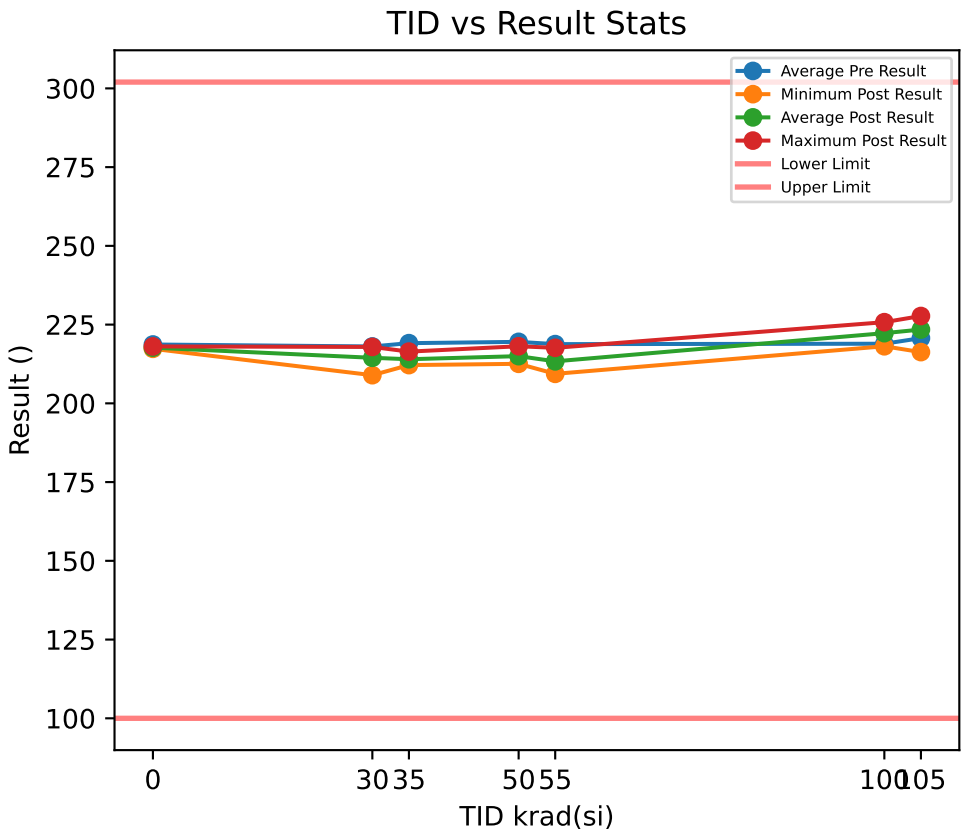
Test Results (Lower Limit = 100.0, Upper Limit = 302.0 ())

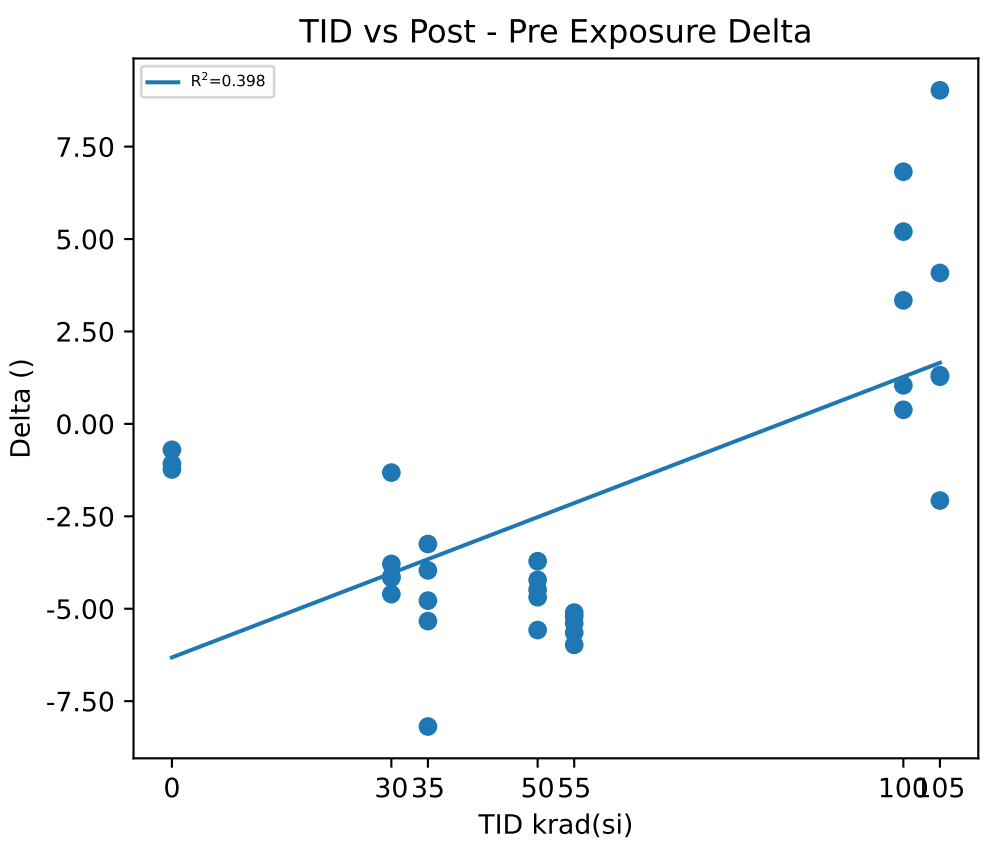
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	213.02	216.07	3.054
2	0	CU2	219.84	217.59	-2.2527
3	0	CU3	213.19	214.3	1.1119
11	30	Unbiased-30krad	216.29	217.2	0.9122
12	30	Unbiased-30krad	212.09	214.17	2.082
13	30	Unbiased-30krad	213.47	213.19	-0.2791
14	30	Unbiased-30krad	213.25	213.04	-0.2156
15	30	Unbiased-30krad	206.99	207.4	0.411
16	35	Biased-30krad	215.84	212.05	-3.7891
17	35	Biased-30krad	218.92	217.41	-1.5156
18	35	Biased-30krad	213.32	211.82	-1.5063
19	35	Biased-30krad	212.58	208.05	-4.5291
20	35	Biased-30krad	216.64	210.54	-6.101
30	50	Unbiased-50krad	215.78	214.4	-1.3797
31	50	Unbiased-50krad	218.27	215.89	-2.3826
32	50	Unbiased-50krad	215.85	213.45	-2.4091
33	50	Unbiased-50krad	220.17	218.54	-1.6251
34	50	Unbiased-50krad	220.42	219.17	-1.2537
40	55	Biased-50krad	219.16	215.84	-3.3246
41	55	Biased-50krad	213.73	211.27	-2.4627
42	55	Biased-50krad	213.43	210.84	-2.5904
43	55	Biased-50krad	214.29	214	-0.2829
44	55	Biased-50krad	219.93	211.7	-8.2322
45	100	Unbiased-100krad	216.96	219.32	2.3587
46	100	Unbiased-100krad	219.78	222.44	2.6666
47	100	Unbiased-100krad	217.49	219.23	1.7344
48	100	Unbiased-100krad	213.82	218.07	4.2439
49	100	Unbiased-100krad	214.73	213.31	-1.4136
50	105	Biased-100krad	212.7	213.05	0.3444
51	105	Biased-100krad	219.41	222.68	3.2704
52	105	Biased-100krad	214.31	220.83	6.5172
53	105	Biased-100krad	217.41	229.07	11.657
54	105	Biased-100krad	217.93	220.02	2.0854

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	213.02	215.35	219.84	3.8919	214.3	215.99	217.59	1.6465	-2.2527	0.63773	3.054	2.6849
30	206.99	212.42	216.29	3.4048	207.4	213	217.2	3.5501	-0.2791	0.5821	2.082	0.9703
35	212.58	215.46	218.92	2.5694	208.05	211.97	217.41	3.4277	-6.101	-3.4882	-1.5063	1.9887
50	215.78	218.1	220.42	2.2443	213.45	216.29	219.17	2.5106	-2.4091	-1.81	-1.2537	0.55127
55	213.43	216.11	219.93	3.1657	210.84	212.73	215.84	2.1249	-8.2322	-3.3786	-0.2829	2.9413
100	213.82	216.56	219.78	2.358	213.31	218.47	222.44	3.3111	-1.4136	1.918	4.2439	2.0795
105	212.7	216.36	219.41	2.7595	213.05	221.13	229.07	5.7467	0.3444	4.7748	11.657	4.4587

Device Test: 47.3 _OnDeadTime|ON_TIME/SW3/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V





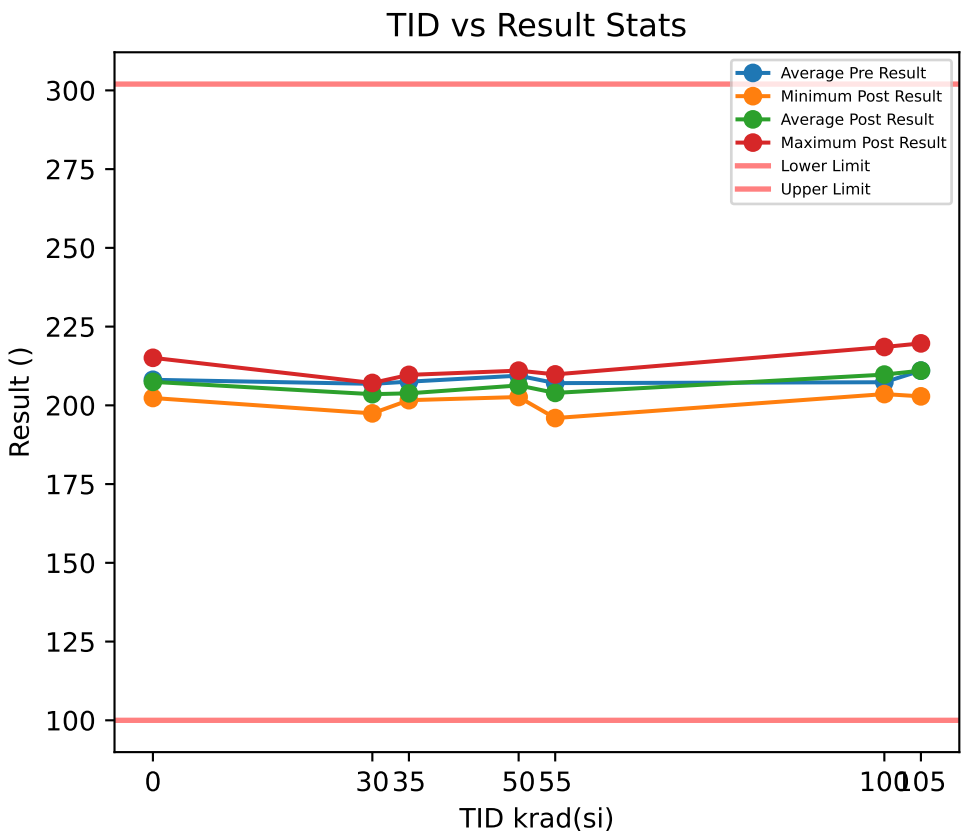
Test Results (Lower Limit = 100.0, Upper Limit = 302.0 ())

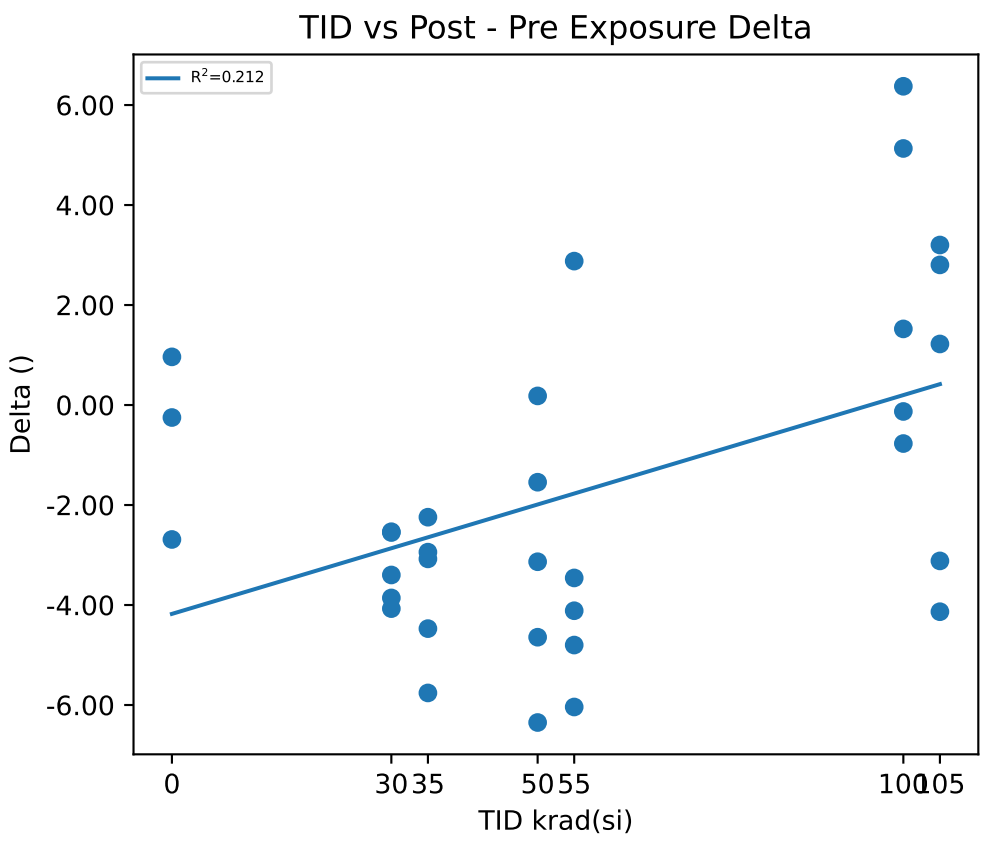
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	218.01	217.31	-0.7011
2	0	CU2	218.74	217.65	-1.0818
3	0	CU3	219.31	218.07	-1.2338
11	30	Unbiased-30krad	219.23	217.91	-1.3174
12	30	Unbiased-30krad	216.99	213.2	-3.7875
13	30	Unbiased-30krad	219.36	214.76	-4.6049
14	30	Unbiased-30krad	221.68	217.51	-4.1634
15	30	Unbiased-30krad	213.07	208.94	-4.1268
16	35	Biased-30krad	220.05	215.27	-4.7805
17	35	Biased-30krad	220.51	212.33	-8.1857
18	35	Biased-30krad	217.12	213.87	-3.249
19	35	Biased-30krad	216.11	212.15	-3.9626
20	35	Biased-30krad	221.76	216.42	-5.3339
30	50	Unbiased-50krad	219.76	215.27	-4.4884
31	50	Unbiased-50krad	220.11	216.39	-3.7149
32	50	Unbiased-50krad	218.17	212.59	-5.577
33	50	Unbiased-50krad	222.81	218.12	-4.689
34	50	Unbiased-50krad	216.77	212.55	-4.2191
40	55	Biased-50krad	222.84	217.63	-5.2146
41	55	Biased-50krad	218.86	213.21	-5.6457
42	55	Biased-50krad	215.34	209.37	-5.9774
43	55	Biased-50krad	218.34	212.95	-5.3897
44	55	Biased-50krad	218.64	213.53	-5.1043
45	100	Unbiased-100krad	217.74	218.12	0.3812
46	100	Unbiased-100krad	218.72	222.06	3.3411
47	100	Unbiased-100krad	218.95	225.77	6.821
48	100	Unbiased-100krad	220.01	225.21	5.2006
49	100	Unbiased-100krad	219.22	220.26	1.0427
50	105	Biased-100krad	218.34	216.27	-2.073
51	105	Biased-100krad	221.42	222.74	1.3167
52	105	Biased-100krad	218.7	227.73	9.0234
53	105	Biased-100krad	222.04	226.12	4.0825
54	105	Biased-100krad	223.02	224.3	1.2756

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	218.01	218.68	219.31	0.64923	217.31	217.68	218.07	0.38205	-1.2338	-1.0056	-0.7011	0.27441
30	213.07	218.06	221.68	3.2482	208.94	214.46	217.91	3.6523	-4.6049	-3.6	-1.3174	1.3086
35	216.11	219.11	221.76	2.3894	212.15	214.01	216.42	1.8537	-8.1857	-5.1023	-3.249	1.8972
50	216.77	219.52	222.81	2.2709	212.55	214.99	218.12	2.427	-5.577	-4.5377	-3.7149	0.68629
55	215.34	218.8	222.84	2.67	209.37	213.34	217.63	2.9312	-5.9774	-5.4663	-5.1043	0.35131
100	217.74	218.93	220.01	0.82289	218.12	222.28	225.77	3.2474	0.3812	3.3573	6.821	2.7207
105	218.34	220.71	223.02	2.0759	216.27	223.43	227.73	4.4213	-2.073	2.725	9.0234	4.1418

Device Test: 47.4 _OnDeadTime|ON_TIME/SW4/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V





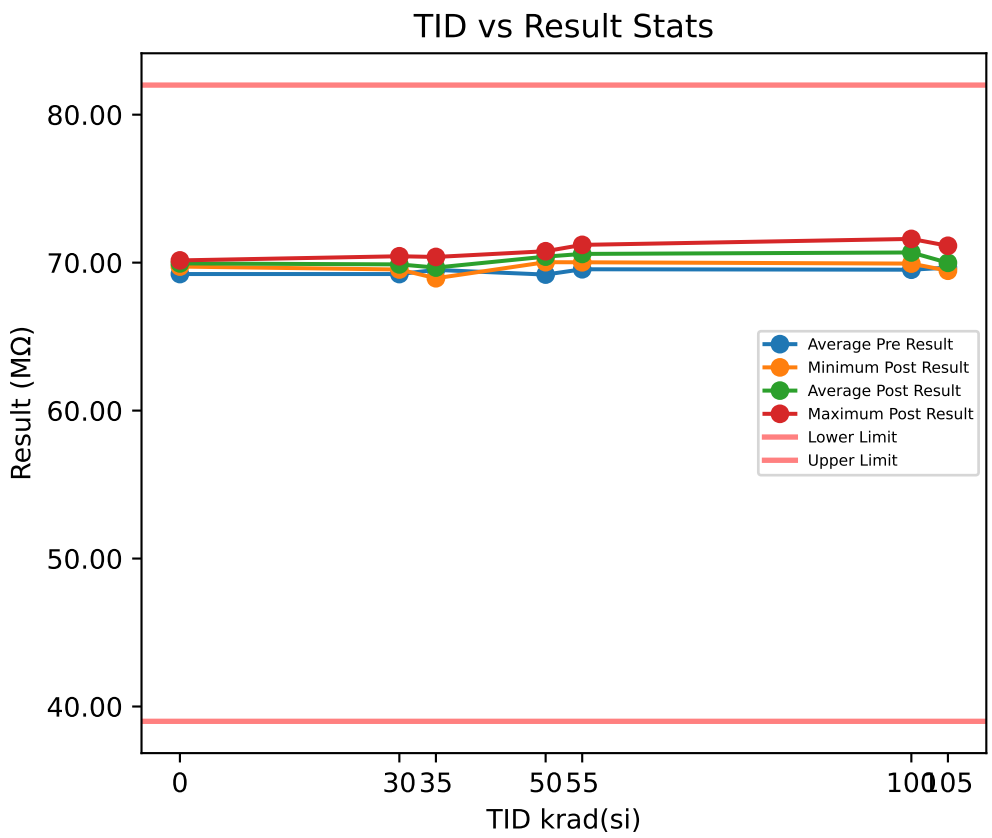
Test Results (Lower Limit = 100.0, Upper Limit = 302.0 ())

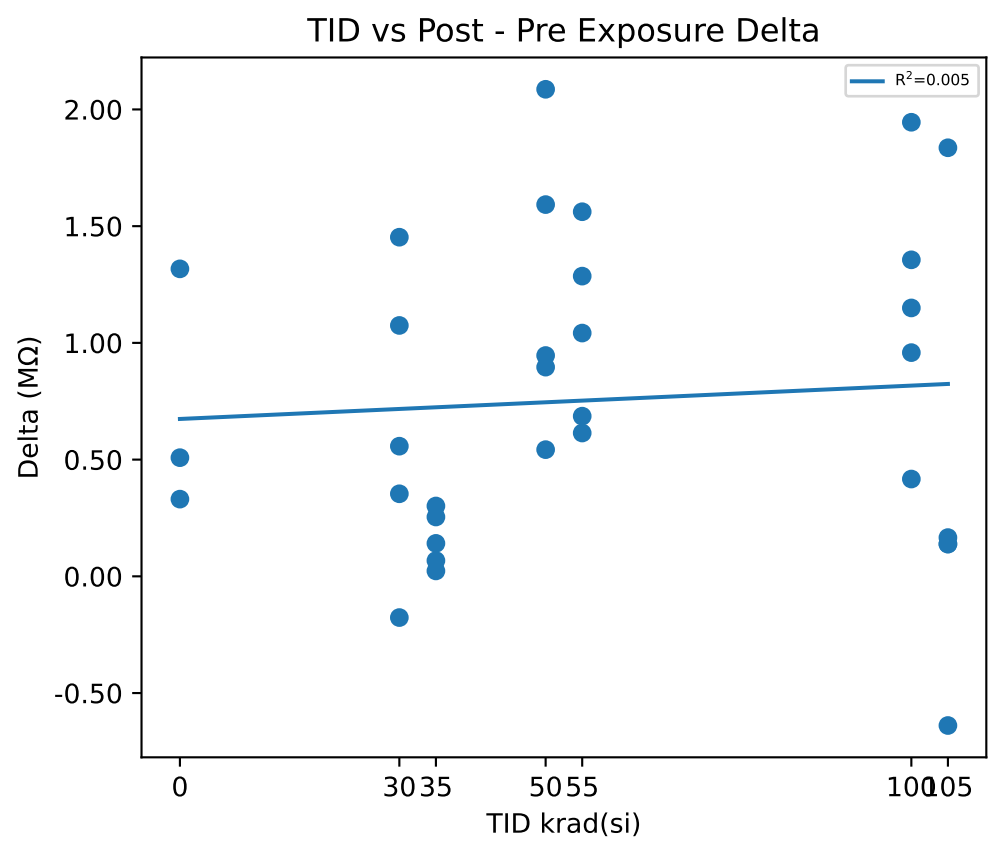
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	205.19	204.94	-0.2498
2	0	CU2	217.78	215.09	-2.689
3	0	CU3	201.37	202.34	0.9632
11	30	Unbiased-30krad	208.5	204.65	-3.8583
12	30	Unbiased-30krad	207.14	204.61	-2.5341
13	30	Unbiased-30krad	211.18	207.11	-4.0721
14	30	Unbiased-30krad	206.45	203.9	-2.5501
15	30	Unbiased-30krad	200.85	197.45	-3.3993
16	35	Biased-30krad	204.77	202.52	-2.2435
17	35	Biased-30krad	206.11	201.64	-4.4722
18	35	Biased-30krad	207.97	202.21	-5.7586
19	35	Biased-30krad	206.12	203.04	-3.0774
20	35	Biased-30krad	212.62	209.67	-2.9426
30	50	Unbiased-50krad	205.74	204.19	-1.5439
31	50	Unbiased-50krad	208.73	205.59	-3.1346
32	50	Unbiased-50krad	207.29	202.64	-4.644
33	50	Unbiased-50krad	217.37	211.02	-6.35
34	50	Unbiased-50krad	207.99	208.18	0.1821
40	55	Biased-50krad	208.66	205.2	-3.4585
41	55	Biased-50krad	202	195.96	-6.0396
42	55	Biased-50krad	204.6	199.8	-4.8008
43	55	Biased-50krad	213.08	208.97	-4.1145
44	55	Biased-50krad	206.95	209.83	2.8784
45	100	Unbiased-100krad	208.18	208.05	-0.1289
46	100	Unbiased-100krad	208.92	210.44	1.5225
47	100	Unbiased-100krad	212.15	218.52	6.375
48	100	Unbiased-100krad	203.11	208.24	5.1314
49	100	Unbiased-100krad	204.35	203.58	-0.7703
50	105	Biased-100krad	205.98	202.86	-3.1179
51	105	Biased-100krad	216.24	212.1	-4.134
52	105	Biased-100krad	209.49	212.3	2.8028
53	105	Biased-100krad	218.45	219.67	1.2211
54	105	Biased-100krad	204.95	208.15	3.2004

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	201.37	208.11	217.78	8.5852	202.34	207.45	215.09	6.7389	-2.689	-0.65853	0.9632	1.8601
30	200.85	206.83	211.18	3.8	197.45	203.54	207.11	3.6171	-4.0721	-3.2828	-2.5341	0.71853
35	204.77	207.52	212.62	3.07	201.64	203.82	209.67	3.3123	-5.7586	-3.6989	-2.2435	1.4068
50	205.74	209.42	217.37	4.5783	202.64	206.32	211.02	3.3213	-6.35	-3.0981	0.1821	2.5564
55	202	207.06	213.08	4.1986	195.96	203.95	209.83	5.966	-6.0396	-3.107	2.8784	3.4797
100	203.11	207.34	212.15	3.6457	203.58	209.76	218.52	5.4928	-0.7703	2.4259	6.375	3.181
105	204.95	211.02	218.45	6.064	202.86	211.02	219.67	6.1759	-4.134	-0.00552	3.2004	3.4059

Device Test: 48.1 _HsRdson|HighSide/SW1/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C





Test Results (Lower Limit = 39.0, Upper Limit = 82.0 (MΩ))

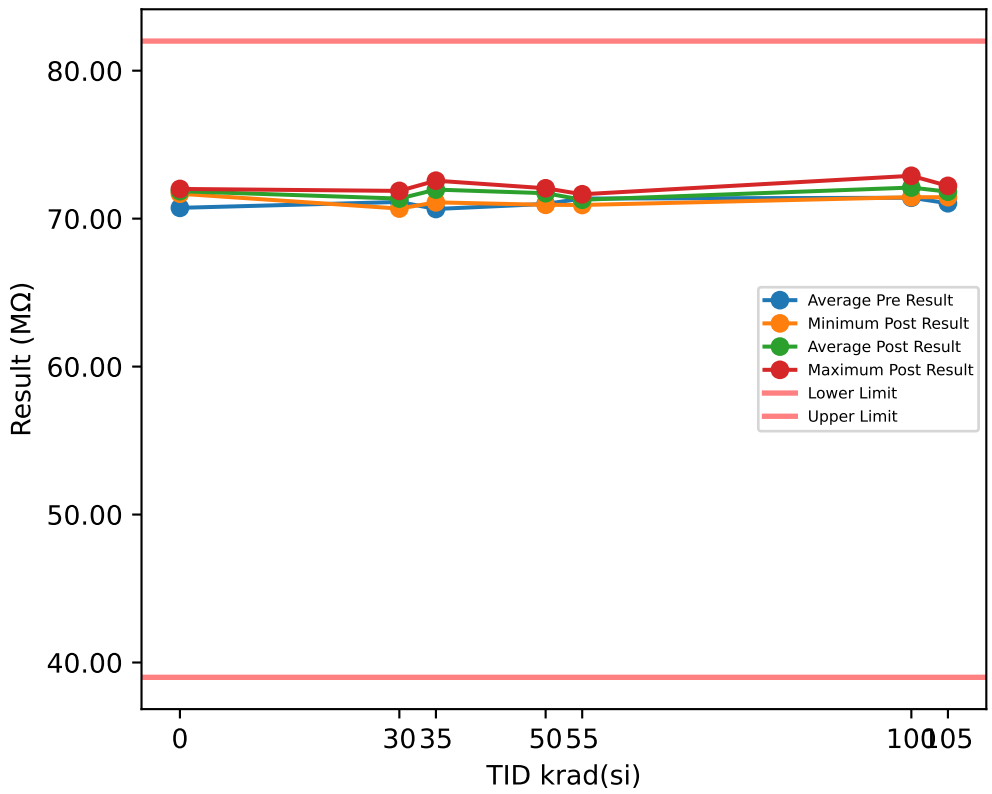
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	68.643	69.96	1.3171
2	0	CU2	69.225	69.733	0.5083
3	0	CU3	69.82	70.151	0.3307
11	30	Unbiased-30krad	68.863	69.938	1.0747
12	30	Unbiased-30krad	69.269	69.623	0.3536
13	30	Unbiased-30krad	69.319	69.877	0.5575
14	30	Unbiased-30krad	68.979	70.431	1.4527
15	30	Unbiased-30krad	69.713	69.536	-0.1766
16	35	Biased-30krad	70.021	70.044	0.0232
17	35	Biased-30krad	70.083	70.384	0.3013
18	35	Biased-30krad	68.803	68.945	0.1412
19	35	Biased-30krad	69.875	69.942	0.0674
20	35	Biased-30krad	68.761	69.015	0.2542
30	50	Unbiased-50krad	69.204	70.15	0.9459
31	50	Unbiased-50krad	69.118	70.71	1.5924
32	50	Unbiased-50krad	69.874	70.771	0.8961
33	50	Unbiased-50krad	69.824	70.367	0.5427
34	50	Unbiased-50krad	67.944	70.03	2.0863
40	55	Biased-50krad	69.79	70.832	1.0421
41	55	Biased-50krad	69.596	70.282	0.6861
42	55	Biased-50krad	69.639	71.201	1.5618
43	55	Biased-50krad	69.324	70.61	1.286
44	55	Biased-50krad	69.41	70.024	0.6139
45	100	Unbiased-100krad	69.658	71.603	1.9451
46	100	Unbiased-100krad	69.519	69.936	0.4168
47	100	Unbiased-100krad	68.801	70.157	1.3558
48	100	Unbiased-100krad	69.425	70.575	1.1497
49	100	Unbiased-100krad	70.206	71.164	0.9583
50	105	Biased-100krad	69.287	69.453	0.166
51	105	Biased-100krad	69.423	69.561	0.138
52	105	Biased-100krad	69.817	69.956	0.1389
53	105	Biased-100krad	70.47	69.831	-0.639
54	105	Biased-100krad	69.302	71.138	1.8358

Test Statistics (MΩ)

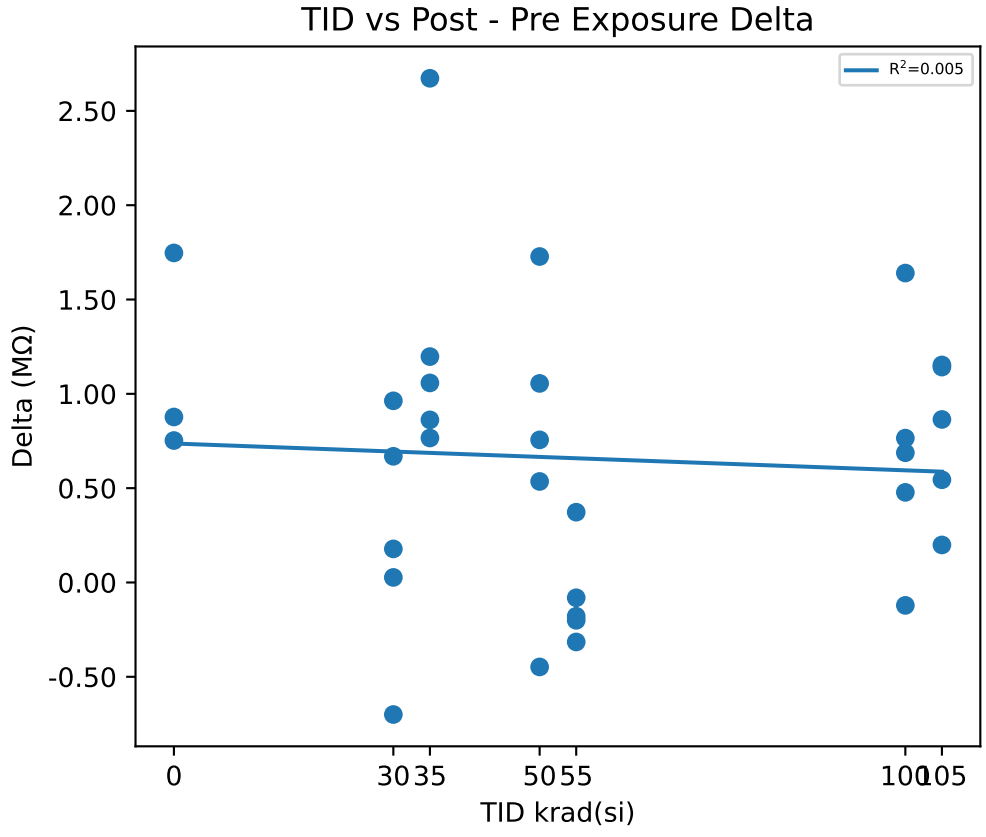
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	68.643	69.229	69.82	0.58871	69.733	69.948	70.151	0.20905	0.3307	0.7187	1.3171	0.52578
30	68.863	69.229	69.713	0.33177	69.536	69.881	70.431	0.35064	-0.1766	0.65238	1.4527	0.63331
35	68.761	69.509	70.083	0.66772	68.945	69.666	70.384	0.64804	0.0232	0.15746	0.3013	0.1188
50	67.944	69.193	69.874	0.77924	70.03	70.405	70.771	0.32939	0.5427	1.2127	2.0863	0.61799
55	69.324	69.552	69.79	0.18604	70.024	70.59	71.201	0.46023	0.6139	1.038	1.5618	0.39987
100	68.801	69.522	70.206	0.50376	69.936	70.687	71.603	0.69372	0.4168	1.1651	1.9451	0.55851
105	69.287	69.66	70.47	0.50092	69.453	69.988	71.138	0.67414	-0.639	0.32794	1.8358	0.90921

Device Test: 48.2 _HsRdson|HighSide/SW2/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



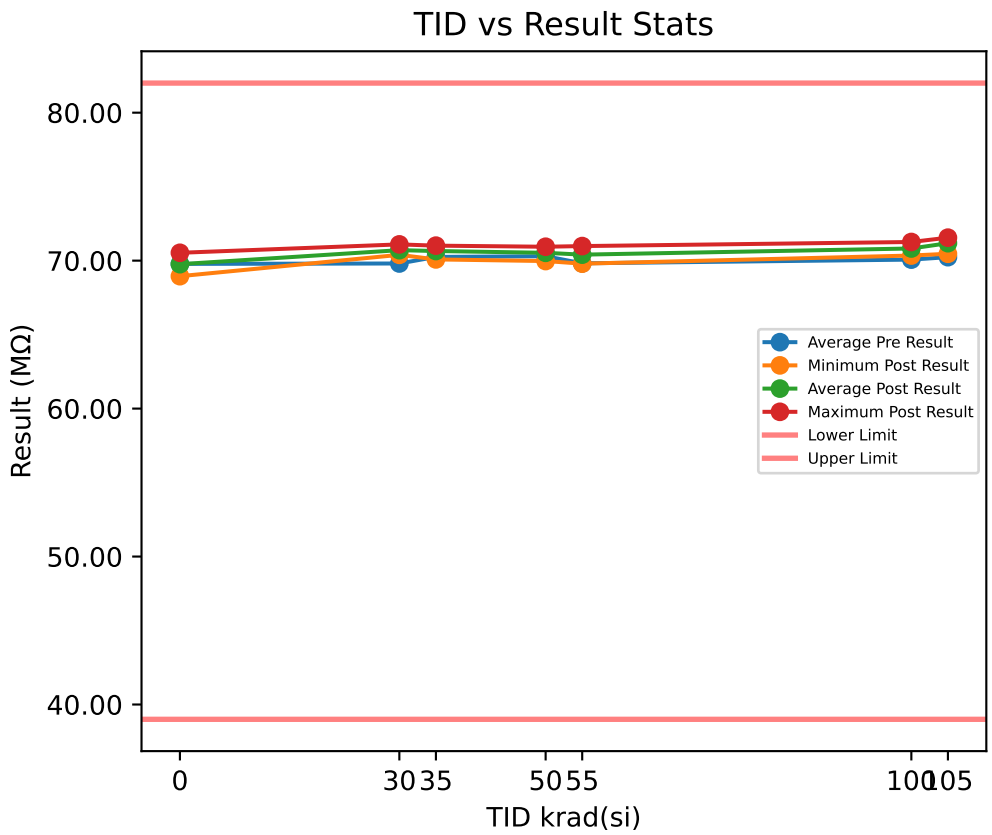
Test Results (Lower Limit = 39.0, Upper Limit = 82.0 (MΩ))

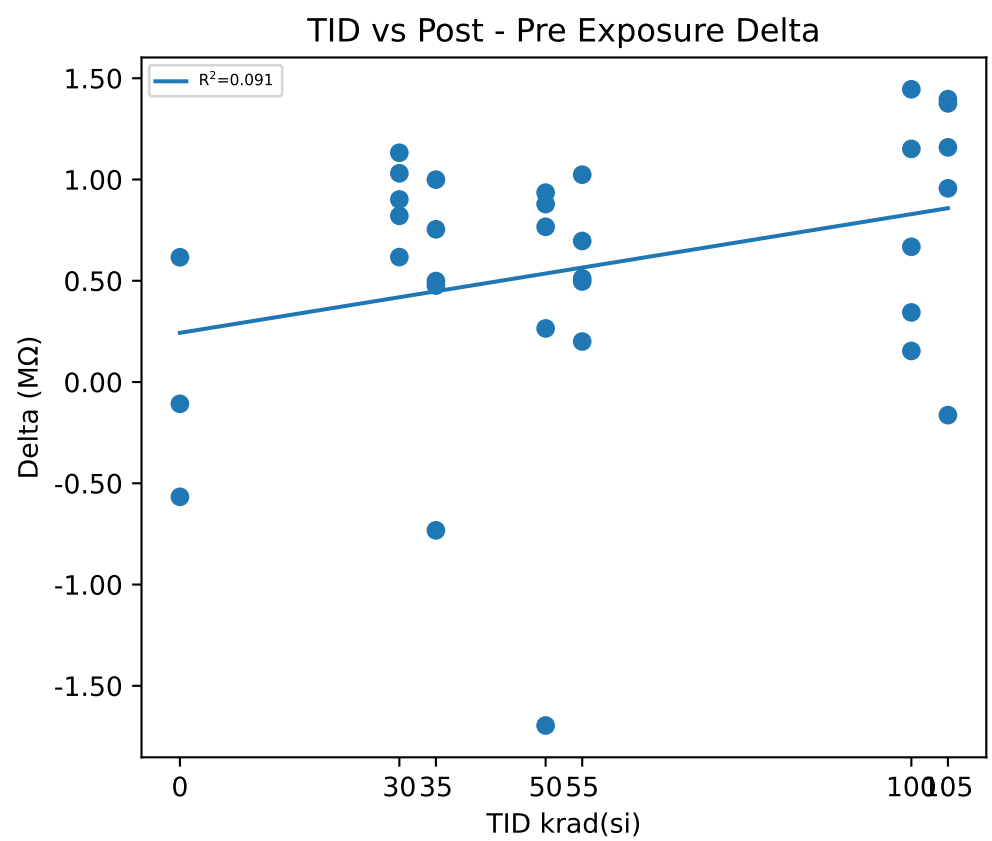
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	70.931	71.683	0.7525
2	0	CU2	70.998	71.875	0.8773
3	0	CU3	70.261	72.008	1.747
11	30	Unbiased-30krad	70.474	71.437	0.963
12	30	Unbiased-30krad	71.206	71.875	0.6689
13	30	Unbiased-30krad	71.38	70.68	-0.6999
14	30	Unbiased-30krad	71.374	71.401	0.0268
15	30	Unbiased-30krad	71.203	71.381	0.178
16	35	Biased-30krad	71.507	72.37	0.862
17	35	Biased-30krad	69.904	71.101	1.1975
18	35	Biased-30krad	69.893	72.566	2.6728
19	35	Biased-30krad	71.306	72.364	1.0579
20	35	Biased-30krad	70.647	71.413	0.766
30	50	Unbiased-50krad	70.794	71.85	1.0553
31	50	Unbiased-50krad	71.381	70.933	-0.4477
32	50	Unbiased-50krad	71.396	71.931	0.5355
33	50	Unbiased-50krad	71.072	71.828	0.756
34	50	Unbiased-50krad	70.324	72.052	1.728
40	55	Biased-50krad	71.275	71.647	0.3726
41	55	Biased-50krad	71.565	71.364	-0.2006
42	55	Biased-50krad	71.761	71.446	-0.3153
43	55	Biased-50krad	71.176	70.997	-0.1789
44	55	Biased-50krad	71.004	70.922	-0.081
45	100	Unbiased-100krad	70.762	71.45	0.6878
46	100	Unbiased-100krad	71.867	72.344	0.4777
47	100	Unbiased-100krad	71.923	71.802	-0.1214
48	100	Unbiased-100krad	71.248	72.014	0.7653
49	100	Unbiased-100krad	71.255	72.896	1.6403
50	105	Biased-100krad	71.669	72.214	0.5446
51	105	Biased-100krad	70.707	71.86	1.1531
52	105	Biased-100krad	70.946	72.088	1.1419
53	105	Biased-100krad	70.627	71.492	0.8642
54	105	Biased-100krad	71.25	71.449	0.1989

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	70.261	70.73	70.998	0.40768	71.683	71.855	72.008	0.16317	0.7525	1.1256	1.747	0.54175
30	70.474	71.127	71.38	0.37547	70.68	71.355	71.875	0.42867	-0.6999	0.22736	0.963	0.64004
35	69.893	70.651	71.507	0.75743	71.101	71.963	72.566	0.65848	0.766	1.3112	2.6728	0.77943
50	70.324	70.994	71.396	0.44891	70.933	71.719	72.052	0.44781	-0.4477	0.72542	1.728	0.79486
55	71.004	71.356	71.761	0.30469	70.922	71.275	71.647	0.30722	-0.3153	-0.08064	0.3726	0.26671
100	70.762	71.411	71.923	0.4851	71.45	72.101	72.896	0.55026	-0.1214	0.68994	1.6403	0.63486
105	70.627	71.04	71.669	0.42735	71.449	71.82	72.214	0.34427	0.1989	0.78054	1.1531	0.40938

Device Test: 48.3 _HsRdson|HighSide/SW3/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C





Test Results (Lower Limit = 39.0, Upper Limit = 82.0 (MΩ))

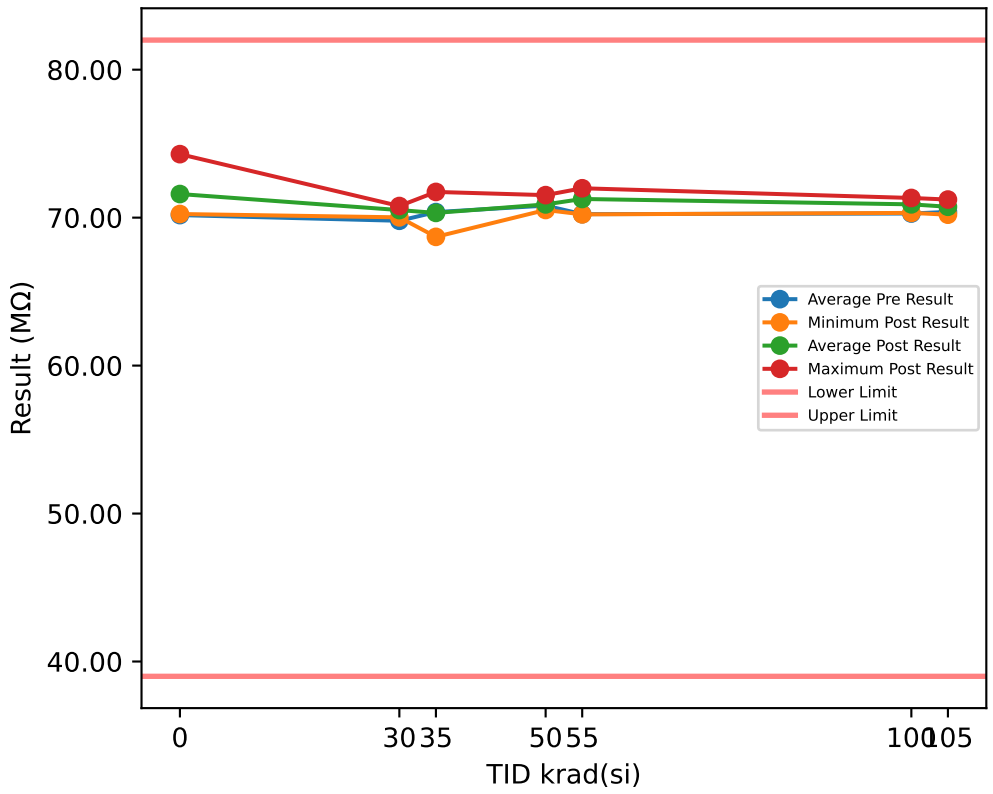
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	69.914	70.53	0.616
2	0	CU2	69.516	68.95	-0.5668
3	0	CU3	69.91	69.802	-0.1076
11	30	Unbiased-30krad	69.638	70.669	1.0307
12	30	Unbiased-30krad	69.571	70.391	0.8208
13	30	Unbiased-30krad	69.523	70.655	1.1322
14	30	Unbiased-30krad	70.196	71.098	0.9016
15	30	Unbiased-30krad	70.108	70.725	0.617
16	35	Biased-30krad	70.399	70.876	0.4763
17	35	Biased-30krad	71.488	70.756	-0.7323
18	35	Biased-30krad	69.584	70.083	0.4987
19	35	Biased-30krad	69.769	70.523	0.7541
20	35	Biased-30krad	70.014	71.013	0.9994
30	50	Unbiased-50krad	69.892	70.658	0.7664
31	50	Unbiased-50krad	69.707	69.972	0.2647
32	50	Unbiased-50krad	69.881	70.816	0.9352
33	50	Unbiased-50krad	70.06	70.939	0.8786
34	50	Unbiased-50krad	71.953	70.257	-1.696
40	55	Biased-50krad	70.106	70.306	0.2001
41	55	Biased-50krad	69.583	70.607	1.0239
42	55	Biased-50krad	69.299	69.795	0.4963
43	55	Biased-50krad	70.288	70.984	0.6964
44	55	Biased-50krad	69.82	70.332	0.512
45	100	Unbiased-100krad	70.192	70.345	0.1534
46	100	Unbiased-100krad	70.176	70.52	0.3438
47	100	Unbiased-100krad	70.1	70.768	0.6677
48	100	Unbiased-100krad	70.062	71.213	1.1512
49	100	Unbiased-100krad	69.815	71.26	1.4455
50	105	Biased-100krad	70.394	71.553	1.1588
51	105	Biased-100krad	69.507	70.464	0.9565
52	105	Biased-100krad	71.226	71.063	-0.1635
53	105	Biased-100krad	69.983	71.38	1.3968
54	105	Biased-100krad	70.062	71.438	1.3761

Test Statistics (MΩ)

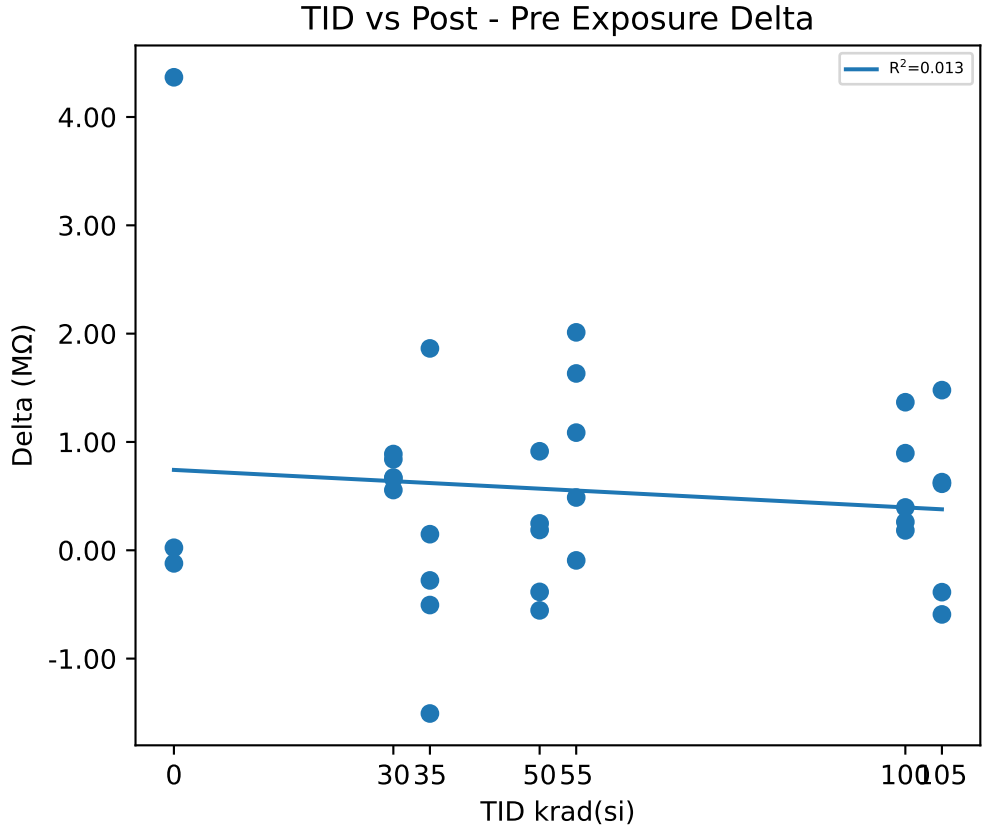
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.516	69.78	69.914	0.22841	68.95	69.761	70.53	0.79093	-0.5668	-0.019467	0.616	0.5963
30	69.523	69.807	70.196	0.31908	70.391	70.708	71.098	0.25343	0.617	0.90046	1.1322	0.19834
35	69.584	70.251	71.488	0.75595	70.083	70.65	71.013	0.36457	-0.7323	0.39924	0.9994	0.66752
50	69.707	70.299	71.953	0.93324	69.972	70.528	70.939	0.40359	-1.696	0.22978	0.9352	1.1086
55	69.299	69.819	70.288	0.39651	69.795	70.405	70.984	0.43686	0.2001	0.58574	1.0239	0.30265
100	69.815	70.069	70.192	0.15178	70.345	70.821	71.26	0.40833	0.1534	0.75232	1.4455	0.54138
105	69.507	70.234	71.226	0.63847	70.464	71.179	71.553	0.43934	-0.1635	0.94494	1.3968	0.64509

Device Test: 48.4 _HsRdson|HighSide/SW4/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 39.0, Upper Limit = 82.0 (MΩ))

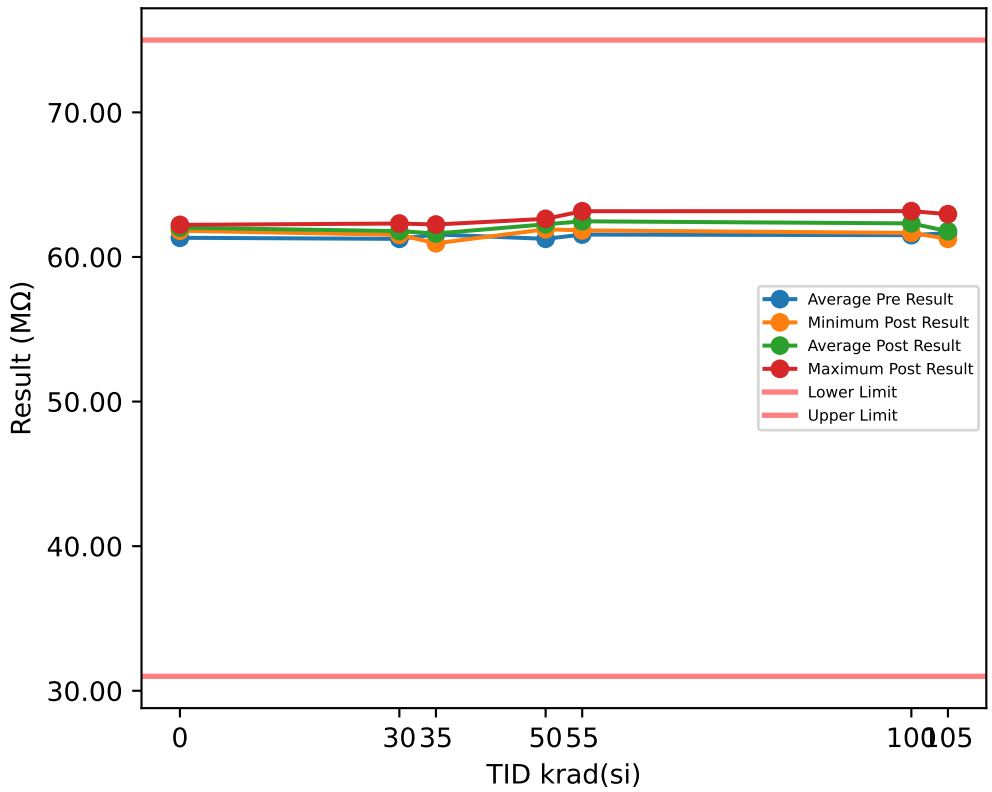
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	70.37	70.249	-0.121
2	0	CU2	69.924	74.291	4.3666
3	0	CU3	70.222	70.245	0.0233
11	30	Unbiased-30krad	69.945	70.784	0.8399
12	30	Unbiased-30krad	69.829	70.501	0.6716
13	30	Unbiased-30krad	69.464	70.02	0.5561
14	30	Unbiased-30krad	69.699	70.587	0.8885
15	30	Unbiased-30krad	70.003	70.665	0.6621
16	35	Biased-30krad	70.52	70.669	0.1485
17	35	Biased-30krad	69.874	71.737	1.8636
18	35	Biased-30krad	70.207	68.701	-1.5069
19	35	Biased-30krad	70.44	69.934	-0.5055
20	35	Biased-30krad	70.837	70.559	-0.2782
30	50	Unbiased-50krad	70.902	70.517	-0.3841
31	50	Unbiased-50krad	70.366	70.614	0.2481
32	50	Unbiased-50krad	71.35	70.796	-0.5549
33	50	Unbiased-50krad	70.607	71.521	0.914
34	50	Unbiased-50krad	70.838	71.025	0.1873
40	55	Biased-50krad	70.648	71.136	0.4872
41	55	Biased-50krad	70.314	70.22	-0.0935
42	55	Biased-50krad	69.953	71.965	2.0118
43	55	Biased-50krad	70.352	71.985	1.6324
44	55	Biased-50krad	69.915	71.001	1.0862
45	100	Unbiased-100krad	69.947	71.314	1.3668
46	100	Unbiased-100krad	71.146	71.33	0.1835
47	100	Unbiased-100krad	70.144	71.04	0.8964
48	100	Unbiased-100krad	69.925	70.32	0.3954
49	100	Unbiased-100krad	70.226	70.487	0.2615
50	105	Biased-100krad	70.925	70.539	-0.3867
51	105	Biased-100krad	69.893	70.522	0.6291
52	105	Biased-100krad	69.717	71.196	1.4785
53	105	Biased-100krad	70.791	70.199	-0.5921
54	105	Biased-100krad	70.608	71.222	0.6141

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	69.924	70.172	70.37	0.22702	70.245	71.595	74.291	2.3348	-0.121	1.423	4.3666	2.5503
30	69.464	69.788	70.003	0.21534	70.02	70.511	70.784	0.29395	0.5561	0.72364	0.8885	0.13717
35	69.874	70.376	70.837	0.35984	68.701	70.32	71.737	1.1135	-1.5069	-0.0557	1.8636	1.2332
50	70.366	70.813	71.35	0.36724	70.517	70.895	71.521	0.40006	-0.5549	0.08208	0.914	0.58176
55	69.915	70.237	70.648	0.30523	70.22	71.261	71.985	0.73929	-0.0935	1.0248	2.0118	0.84952
100	69.925	70.278	71.146	0.50216	70.32	70.898	71.33	0.46949	0.1835	0.62072	1.3668	0.5009
105	69.717	70.387	70.925	0.54661	70.199	70.736	71.222	0.45283	-0.5921	0.34858	1.4785	0.84431

Device Test: 49.1 _HsRdson|HighSide/SW1/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C

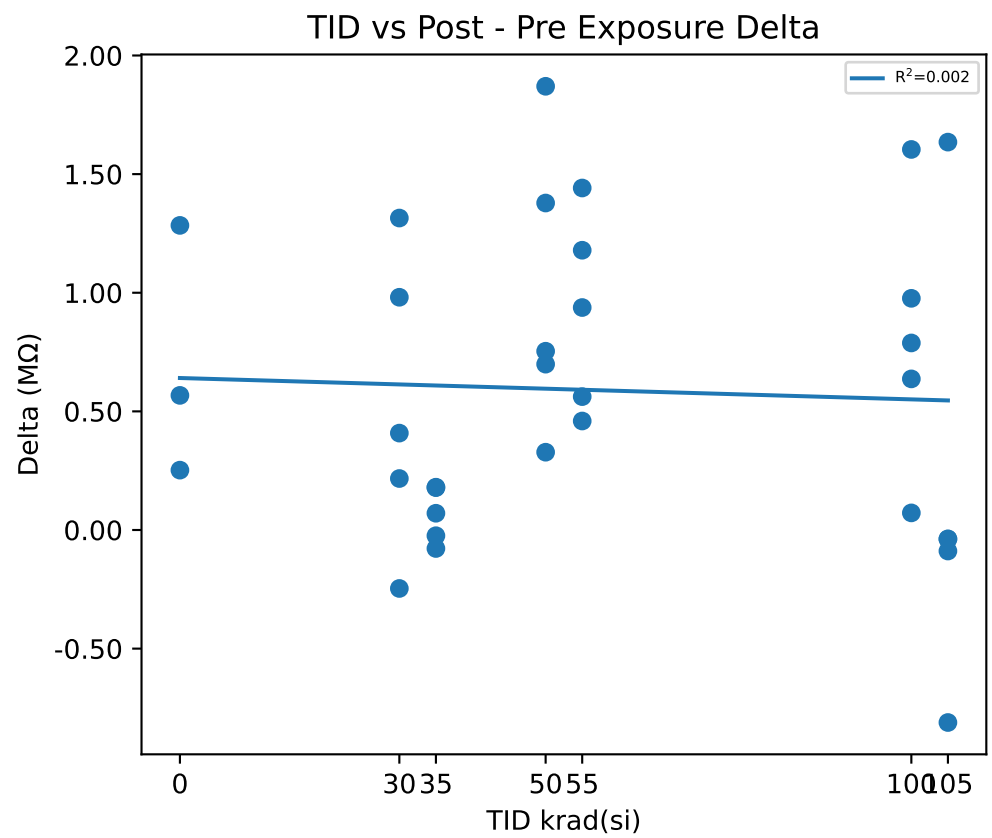
TID vs Result Stats



Test Results (Lower Limit = 31.0, Upper Limit = 75.0 (MΩ))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	60.764	62.048	1.2839
2	0	CU2	61.249	61.816	0.5674
3	0	CU3	61.969	62.221	0.2523
11	30	Unbiased-30krad	60.833	61.814	0.981
12	30	Unbiased-30krad	61.413	61.63	0.217
13	30	Unbiased-30krad	61.239	61.647	0.4084
14	30	Unbiased-30krad	60.999	62.314	1.3149
15	30	Unbiased-30krad	61.779	61.532	-0.2464
16	35	Biased-30krad	62.082	62.004	-0.0779
17	35	Biased-30krad	62.066	62.245	0.1786
18	35	Biased-30krad	61.019	61.09	0.0706
19	35	Biased-30krad	61.853	61.829	-0.0241
20	35	Biased-30krad	60.765	60.945	0.1804
30	50	Unbiased-50krad	61.341	62.094	0.7535
31	50	Unbiased-50krad	61.107	62.485	1.3782
32	50	Unbiased-50krad	61.941	62.639	0.699
33	50	Unbiased-50krad	61.84	62.168	0.3279
34	50	Unbiased-50krad	60.044	61.914	1.8702
40	55	Biased-50krad	61.729	62.666	0.9377
41	55	Biased-50krad	61.563	62.125	0.5622
42	55	Biased-50krad	61.722	63.164	1.4415
43	55	Biased-50krad	61.362	62.541	1.1792
44	55	Biased-50krad	61.379	61.838	0.4594
45	100	Unbiased-100krad	61.568	63.172	1.604
46	100	Unbiased-100krad	61.595	61.667	0.0721
47	100	Unbiased-100krad	60.739	61.716	0.9765
48	100	Unbiased-100krad	61.371	62.16	0.7884
49	100	Unbiased-100krad	62.268	62.905	0.6369
50	105	Biased-100krad	61.293	61.255	-0.0383
51	105	Biased-100krad	61.331	61.293	-0.0376
52	105	Biased-100krad	61.883	61.794	-0.0886
53	105	Biased-100krad	62.415	61.603	-0.8114
54	105	Biased-100krad	61.327	62.962	1.6349

TID vs Post - Pre Exposure Delta

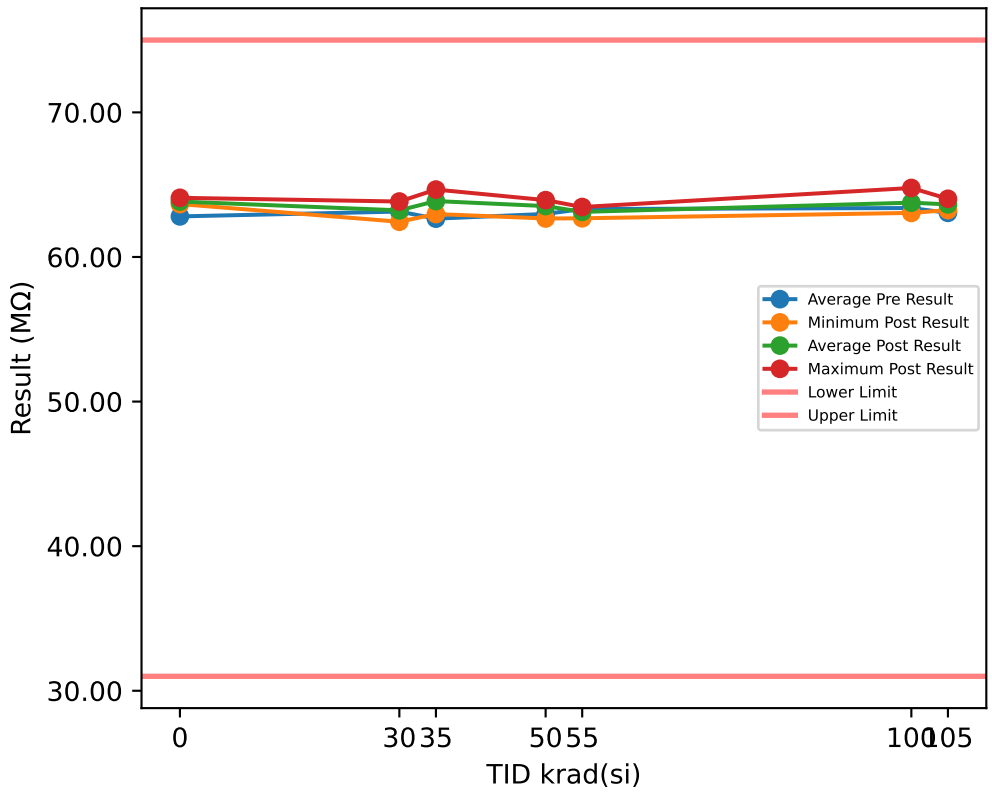


Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	60.764	61.327	61.969	0.60631	61.816	62.028	62.221	0.20314	0.2523	0.7012	1.2839	0.52866
30	60.833	61.253	61.779	0.36834	61.532	61.788	62.314	0.31141	-0.2464	0.53498	1.3149	0.61945
35	60.765	61.557	62.082	0.62032	60.945	61.623	62.245	0.57399	-0.0779	0.06552	0.1804	0.11685
50	60.044	61.254	61.941	0.75965	61.914	62.26	62.639	0.29603	0.3279	1.0058	1.8702	0.61303
55	61.362	61.551	61.729	0.17795	61.838	62.467	63.164	0.51068	0.4594	0.916	1.4415	0.41218
100	60.739	61.508	62.268	0.54734	61.667	62.324	63.172	0.6866	0.0721	0.81558	1.604	0.55519
105	61.293	61.65	62.415	0.493	61.255	61.782	62.962	0.69667	-0.8114	0.1318	1.6349	0.9021

Device Test: 49.2 _HsRdson|HighSide/SW2/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C

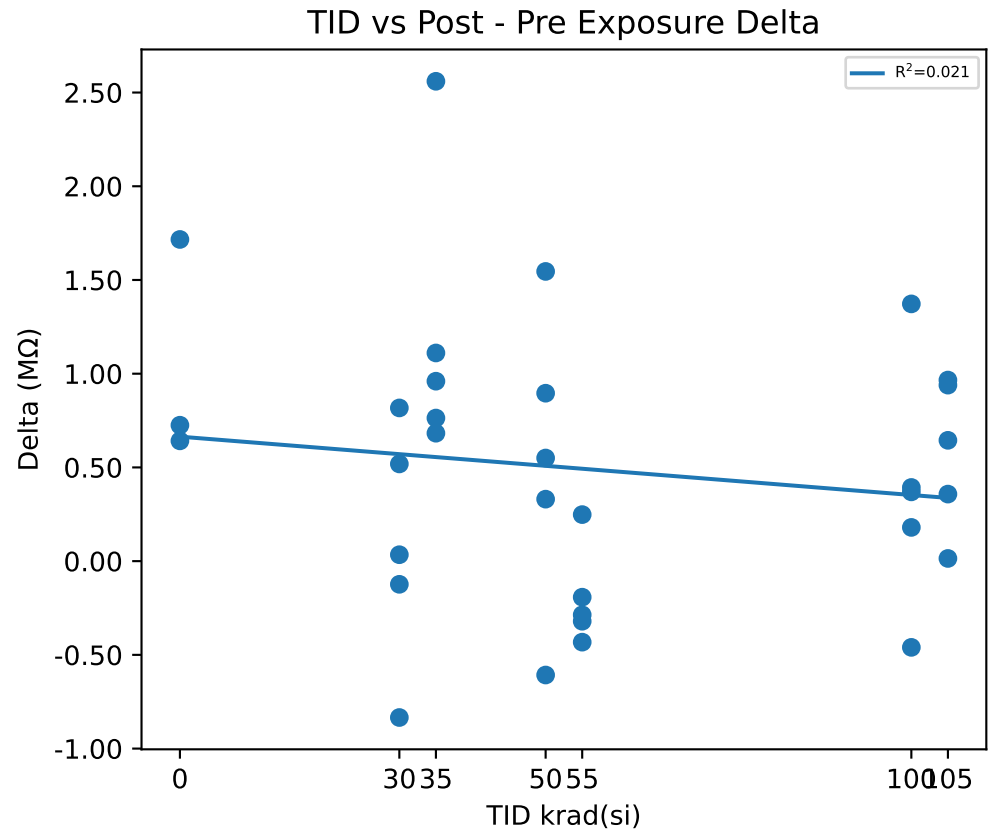
TID vs Result Stats



Test Results (Lower Limit = 31.0, Upper Limit = 75.0 (MΩ))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	63.027	63.752	0.7252
2	0	CU2	63.017	63.659	0.6417
3	0	CU3	62.376	64.092	1.7162
11	30	Unbiased-30krad	62.45	63.267	0.8174
12	30	Unbiased-30krad	63.317	63.836	0.5186
13	30	Unbiased-30krad	63.271	62.437	-0.8342
14	30	Unbiased-30krad	63.35	63.226	-0.1236
15	30	Unbiased-30krad	63.322	63.356	0.0343
16	35	Biased-30krad	63.505	64.268	0.7634
17	35	Biased-30krad	61.859	62.969	1.1106
18	35	Biased-30krad	62.102	64.662	2.56
19	35	Biased-30krad	63.221	64.181	0.96
20	35	Biased-30krad	62.57	63.253	0.6825
30	50	Unbiased-50krad	62.809	63.705	0.8959
31	50	Unbiased-50krad	63.27	62.662	-0.6075
32	50	Unbiased-50krad	63.388	63.719	0.3307
33	50	Unbiased-50krad	63.032	63.583	0.5502
34	50	Unbiased-50krad	62.386	63.932	1.5456
40	55	Biased-50krad	63.208	63.456	0.2483
41	55	Biased-50krad	63.499	63.212	-0.2864
42	55	Biased-50krad	63.826	63.394	-0.4322
43	55	Biased-50krad	63.179	62.858	-0.3206
44	55	Biased-50krad	62.868	62.676	-0.1923
45	100	Unbiased-100krad	62.679	63.048	0.3695
46	100	Unbiased-100krad	63.872	64.052	0.18
47	100	Unbiased-100krad	63.812	63.352	-0.46
48	100	Unbiased-100krad	63.162	63.555	0.3931
49	100	Unbiased-100krad	63.4	64.773	1.3724
50	105	Biased-100krad	63.666	64.024	0.3577
51	105	Biased-100krad	62.679	63.645	0.9661
52	105	Biased-100krad	63.01	63.949	0.939
53	105	Biased-100krad	62.597	63.242	0.6446
54	105	Biased-100krad	63.313	63.328	0.0144

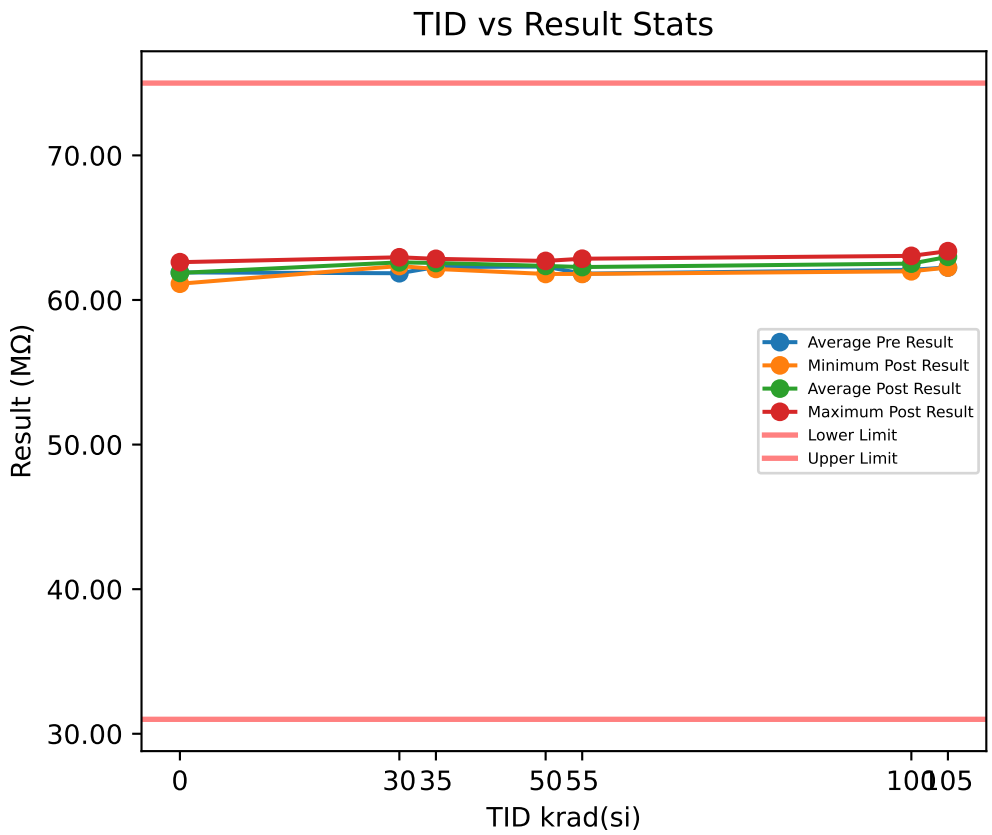
TID vs Post - Pre Exposure Delta

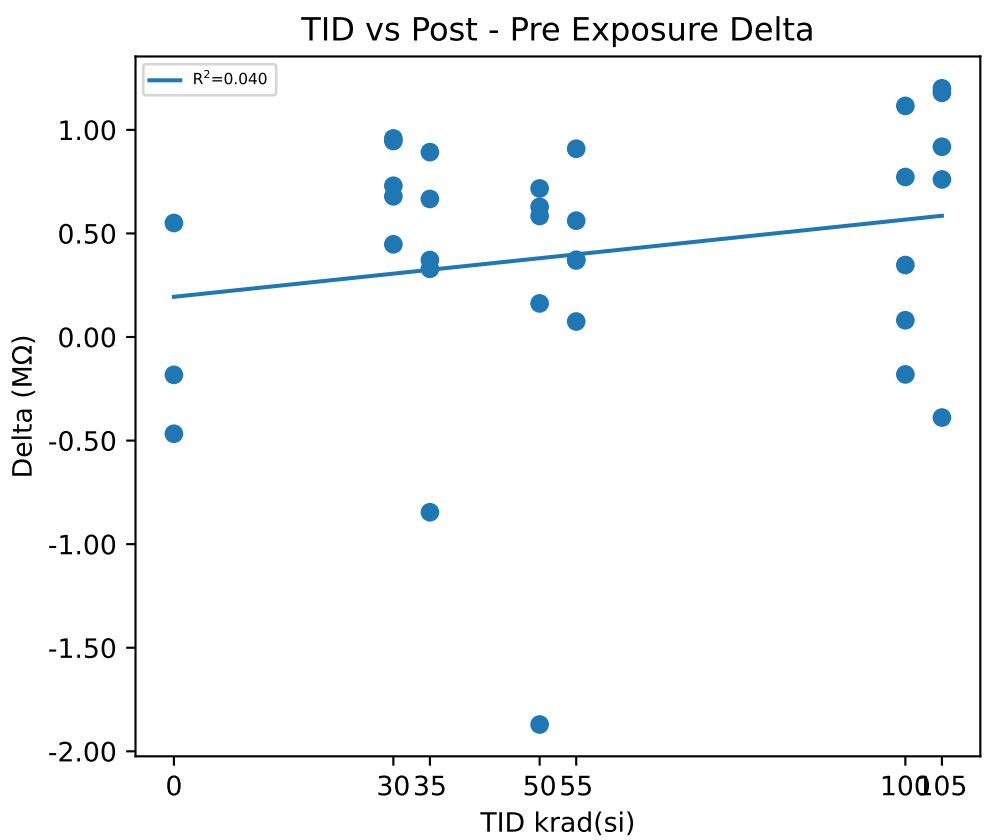


Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.376	62.806	63.027	0.37297	63.659	63.834	64.092	0.22813	0.6417	1.0277	1.7162	0.59772
30	62.45	63.142	63.35	0.388	62.437	63.224	63.836	0.50324	-0.8342	0.0825	0.8174	0.63549
35	61.859	62.652	63.505	0.70534	62.969	63.867	64.662	0.72018	0.6825	1.2153	2.56	0.77014
50	62.386	62.977	63.388	0.39834	62.662	63.52	63.932	0.49588	-0.6075	0.54298	1.5456	0.79034
55	62.868	63.316	63.826	0.36215	62.676	63.119	63.456	0.33997	-0.4322	-0.19664	0.2483	0.26311
100	62.679	63.385	63.872	0.49188	63.048	63.756	64.773	0.67565	-0.46	0.371	1.3724	0.65771
105	62.597	63.053	63.666	0.44558	63.242	63.637	64.024	0.35341	0.0144	0.58436	0.9661	0.40353

Device Test: 49.3 _HsRdson|HighSide/SW3/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C





Test Results (Lower Limit = 31.0, Upper Limit = 75.0 (MΩ))

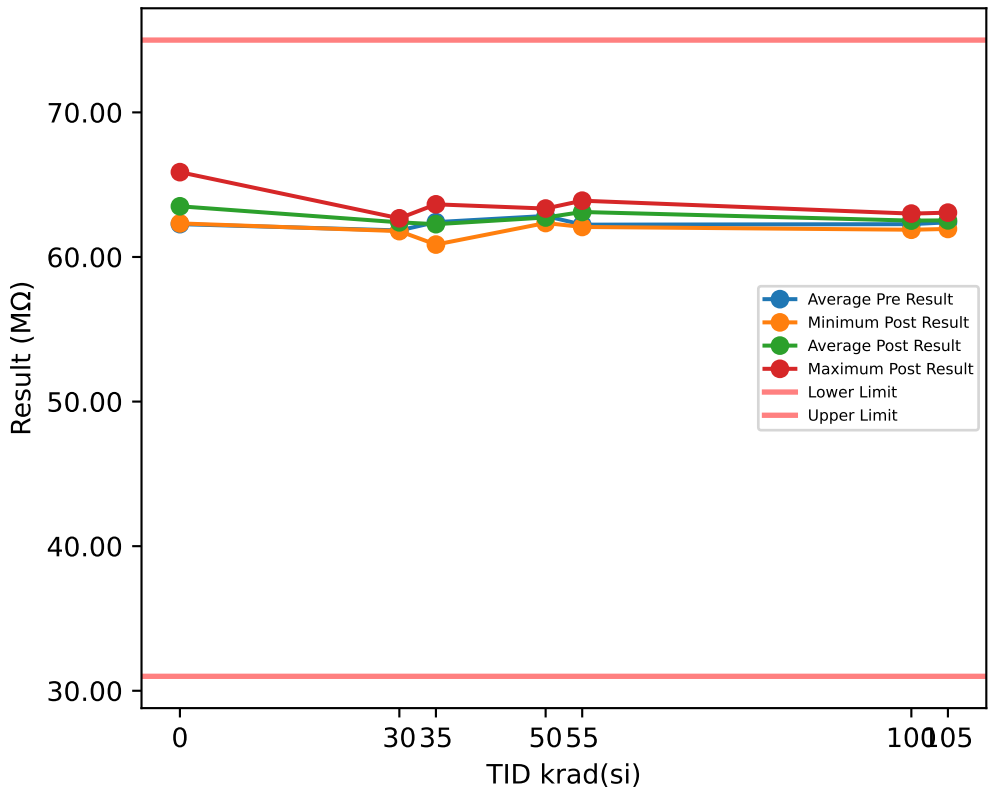
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	62.064	62.614	0.5505
2	0	CU2	61.592	61.125	-0.467
3	0	CU3	62.06	61.877	-0.1827
11	30	Unbiased-30krad	61.636	62.582	0.9461
12	30	Unbiased-30krad	61.669	62.348	0.6792
13	30	Unbiased-30krad	61.46	62.419	0.9587
14	30	Unbiased-30krad	62.223	62.953	0.7302
15	30	Unbiased-30krad	62.262	62.71	0.4474
16	35	Biased-30krad	62.456	62.828	0.3717
17	35	Biased-30krad	63.472	62.626	-0.8459
18	35	Biased-30krad	61.818	62.147	0.3293
19	35	Biased-30krad	61.684	62.35	0.6665
20	35	Biased-30krad	61.953	62.846	0.8925
30	50	Unbiased-50krad	61.908	62.492	0.5841
31	50	Unbiased-50krad	61.637	61.799	0.1622
32	50	Unbiased-50krad	61.913	62.63	0.7172
33	50	Unbiased-50krad	62.073	62.701	0.6285
34	50	Unbiased-50krad	64.029	62.159	-1.8706
40	55	Biased-50krad	62.051	62.126	0.0748
41	55	Biased-50krad	61.575	62.484	0.9089
42	55	Biased-50krad	61.428	61.801	0.3731
43	55	Biased-50krad	62.292	62.853	0.5616
44	55	Biased-50krad	61.752	62.121	0.3695
45	100	Unbiased-100krad	62.164	61.983	-0.1806
46	100	Unbiased-100krad	62.224	62.305	0.0809
47	100	Unbiased-100krad	62.06	62.408	0.3474
48	100	Unbiased-100krad	62.055	62.827	0.7724
49	100	Unbiased-100krad	61.935	63.05	1.1157
50	105	Biased-100krad	62.457	63.376	0.9185
51	105	Biased-100krad	61.483	62.244	0.7607
52	105	Biased-100krad	63.306	62.917	-0.3888
53	105	Biased-100krad	61.903	63.103	1.2007
54	105	Biased-100krad	62.099	63.278	1.1788

Test Statistics (MΩ)

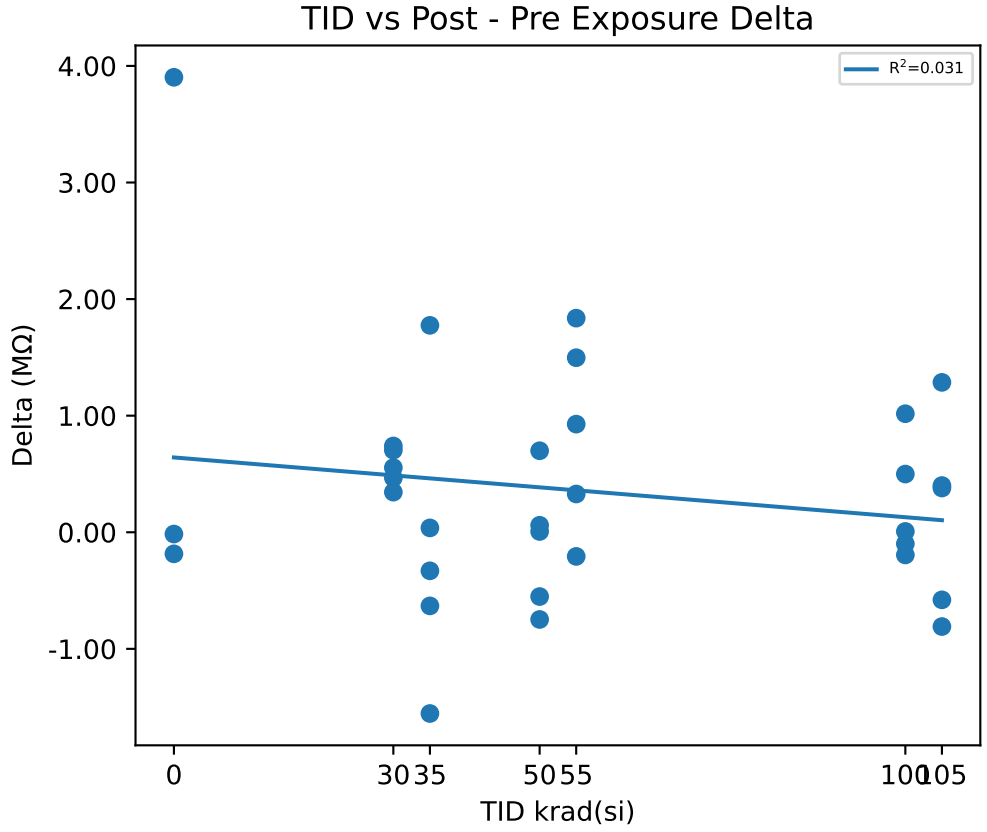
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.592	61.905	62.064	0.27122	61.125	61.872	62.614	0.74451	-0.467	-0.033067	0.5505	0.52499
30	61.46	61.85	62.262	0.36732	62.348	62.602	62.953	0.24156	0.4474	0.75232	0.9587	0.21152
35	61.684	62.277	63.472	0.72935	62.147	62.559	62.846	0.30507	-0.8459	0.28282	0.8925	0.67138
50	61.637	62.312	64.029	0.9727	61.799	62.356	62.701	0.37479	-1.8706	0.04428	0.7172	1.0916
55	61.428	61.82	62.292	0.35146	61.801	62.277	62.853	0.40256	0.0748	0.45758	0.9089	0.30656
100	61.935	62.088	62.224	0.11142	61.983	62.515	63.05	0.42493	-0.1806	0.42716	1.1157	0.52175
105	61.483	62.25	63.306	0.68742	62.244	62.984	63.376	0.44901	-0.3888	0.73398	1.2007	0.65404

Device Test: 49.4 _HsRdson|HighSide/SW4/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 31.0, Upper Limit = 75.0 (MΩ))

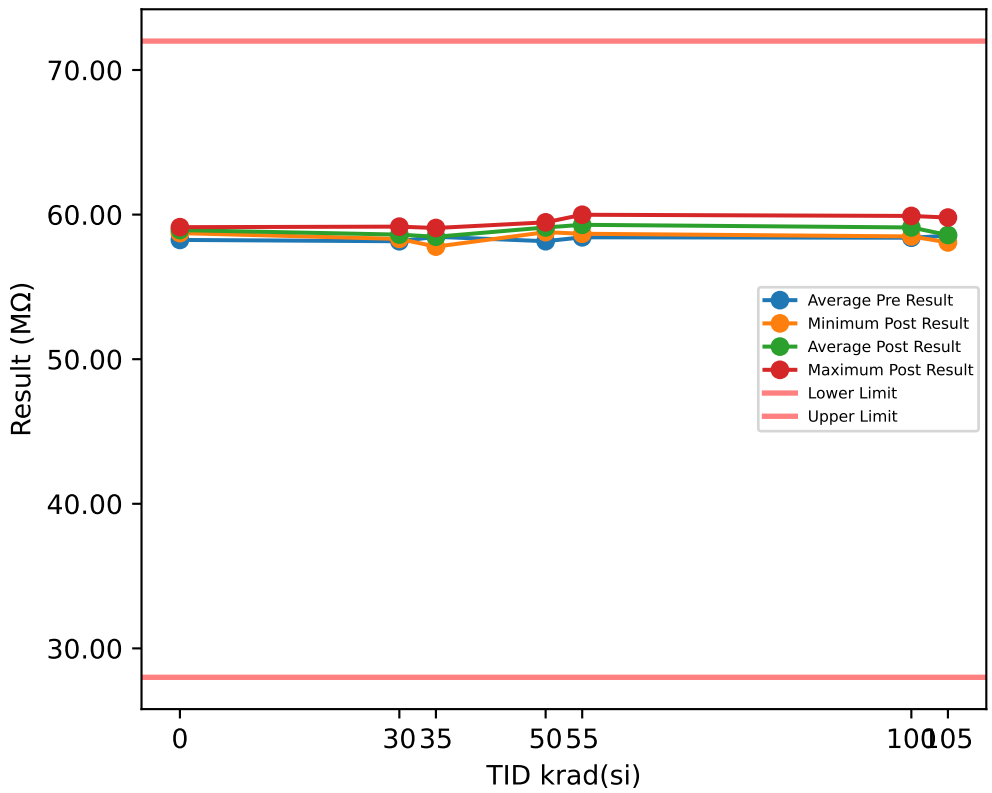
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	62.508	62.323	-0.185
2	0	CU2	61.964	65.867	3.9025
3	0	CU3	62.342	62.327	-0.0153
11	30	Unbiased-30krad	61.912	62.616	0.7041
12	30	Unbiased-30krad	61.91	62.464	0.5542
13	30	Unbiased-30krad	61.444	61.788	0.3441
14	30	Unbiased-30krad	61.703	62.443	0.7402
15	30	Unbiased-30krad	62.208	62.675	0.4672
16	35	Biased-30krad	62.585	62.622	0.0373
17	35	Biased-30krad	61.866	63.641	1.7748
18	35	Biased-30krad	62.414	60.859	-1.5546
19	35	Biased-30krad	62.391	61.76	-0.6315
20	35	Biased-30krad	62.789	62.458	-0.3307
30	50	Unbiased-50krad	62.937	62.385	-0.5514
31	50	Unbiased-50krad	62.289	62.349	0.0599
32	50	Unbiased-50krad	63.377	62.63	-0.7479
33	50	Unbiased-50krad	62.651	63.35	0.6992
34	50	Unbiased-50krad	62.934	62.941	0.0067
40	55	Biased-50krad	62.614	62.942	0.3282
41	55	Biased-50krad	62.283	62.076	-0.2071
42	55	Biased-50krad	62.028	63.864	1.8366
43	55	Biased-50krad	62.396	63.894	1.4973
44	55	Biased-50krad	61.855	62.783	0.9275
45	100	Unbiased-100krad	61.875	62.891	1.0168
46	100	Unbiased-100krad	63.194	63	-0.1944
47	100	Unbiased-100krad	62.106	62.605	0.4993
48	100	Unbiased-100krad	61.877	61.884	0.0071
49	100	Unbiased-100krad	62.297	62.199	-0.0987
50	105	Biased-100krad	62.971	62.391	-0.5796
51	105	Biased-100krad	61.833	62.212	0.3795
52	105	Biased-100krad	61.768	63.054	1.2857
53	105	Biased-100krad	62.747	61.939	-0.8087
54	105	Biased-100krad	62.666	63.067	0.4008

Test Statistics (MΩ)

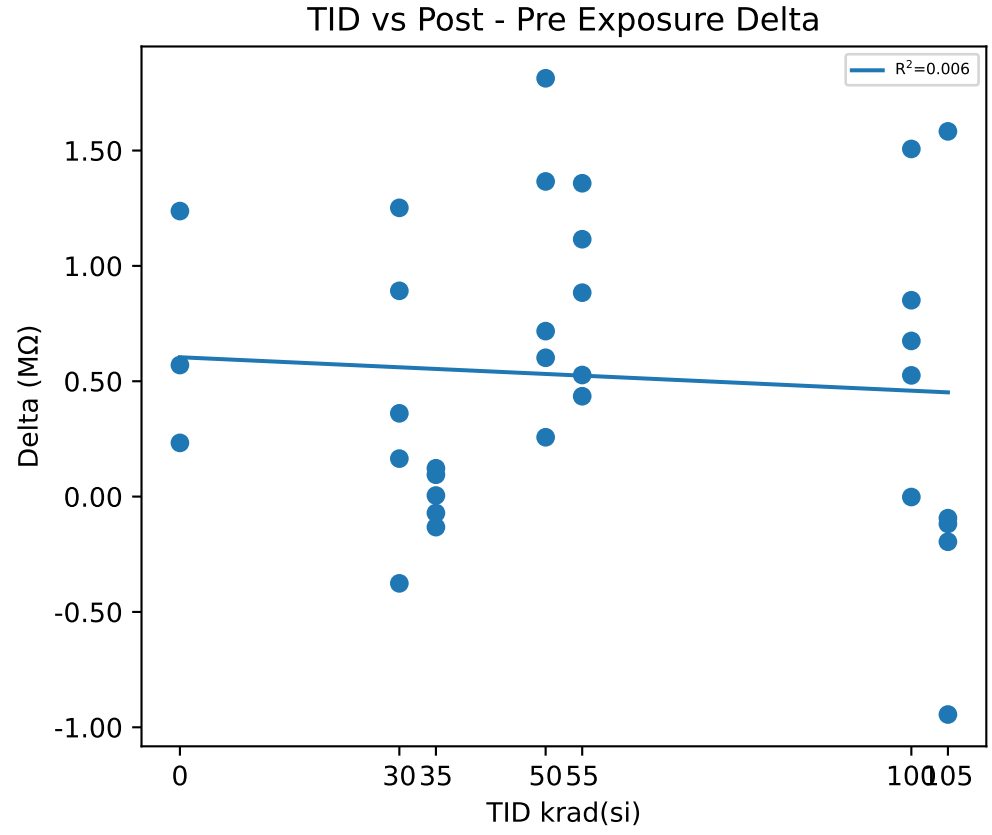
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	61.964	62.272	62.508	0.27874	62.323	63.506	65.867	2.0449	-0.185	1.2341	3.9025	2.3125
30	61.444	61.835	62.208	0.28333	61.788	62.397	62.675	0.35459	0.3441	0.56196	0.7402	0.16468
35	61.866	62.409	62.789	0.34291	60.859	62.268	63.641	1.0356	-1.5546	-0.14094	1.7748	1.2224
50	62.289	62.838	63.377	0.40206	62.349	62.731	63.35	0.41907	-0.7479	-0.1067	0.6992	0.56987
55	61.855	62.235	62.614	0.29973	62.076	63.112	63.894	0.77249	-0.2071	0.8765	1.8366	0.83436
100	61.875	62.27	63.194	0.54604	61.884	62.516	63	0.46976	-0.1944	0.24602	1.0168	0.50699
105	61.768	62.397	62.971	0.55641	61.939	62.533	63.067	0.50799	-0.8087	0.13554	1.2857	0.84495

Device Test: 50.1 _HsRdson|HighSide/SW1/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 28.0, Upper Limit = 72.0 (MΩ))

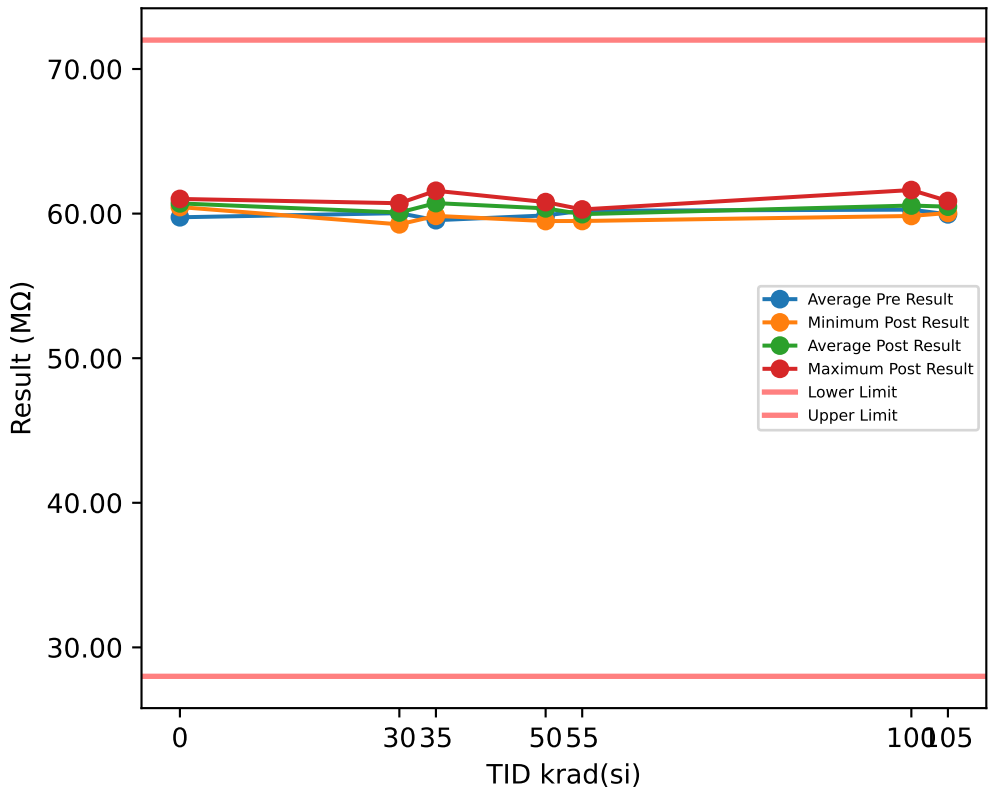
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	57.697	58.934	1.2377
2	0	CU2	58.151	58.721	0.5702
3	0	CU3	58.898	59.131	0.2328
11	30	Unbiased-30krad	57.731	58.623	0.8919
12	30	Unbiased-30krad	58.356	58.521	0.1646
13	30	Unbiased-30krad	58.088	58.449	0.3609
14	30	Unbiased-30krad	57.916	59.168	1.2516
15	30	Unbiased-30krad	58.693	58.317	-0.3761
16	35	Biased-30krad	58.973	58.84	-0.1324
17	35	Biased-30krad	58.951	59.074	0.1228
18	35	Biased-30krad	57.977	57.982	0.0046
19	35	Biased-30krad	58.727	58.656	-0.0711
20	35	Biased-30krad	57.691	57.786	0.0947
30	50	Unbiased-50krad	58.262	58.979	0.7172
31	50	Unbiased-50krad	57.962	59.328	1.3661
32	50	Unbiased-50krad	58.864	59.465	0.6017
33	50	Unbiased-50krad	58.739	58.997	0.2572
34	50	Unbiased-50krad	56.971	58.785	1.8132
40	55	Biased-50krad	58.59	59.474	0.8839
41	55	Biased-50krad	58.429	58.956	0.527
42	55	Biased-50krad	58.631	59.989	1.3582
43	55	Biased-50krad	58.259	59.374	1.1156
44	55	Biased-50krad	58.24	58.675	0.435
45	100	Unbiased-100krad	58.401	59.907	1.5069
46	100	Unbiased-100krad	58.493	58.492	-0.0019
47	100	Unbiased-100krad	57.648	58.499	0.8511
48	100	Unbiased-100krad	58.259	58.934	0.6747
49	100	Unbiased-100krad	59.2	59.725	0.5254
50	105	Biased-100krad	58.18	58.087	-0.0935
51	105	Biased-100krad	58.193	58.075	-0.1182
52	105	Biased-100krad	58.801	58.605	-0.1957
53	105	Biased-100krad	59.324	58.38	-0.9446
54	105	Biased-100krad	58.212	59.796	1.5831

Test Statistics (MΩ)

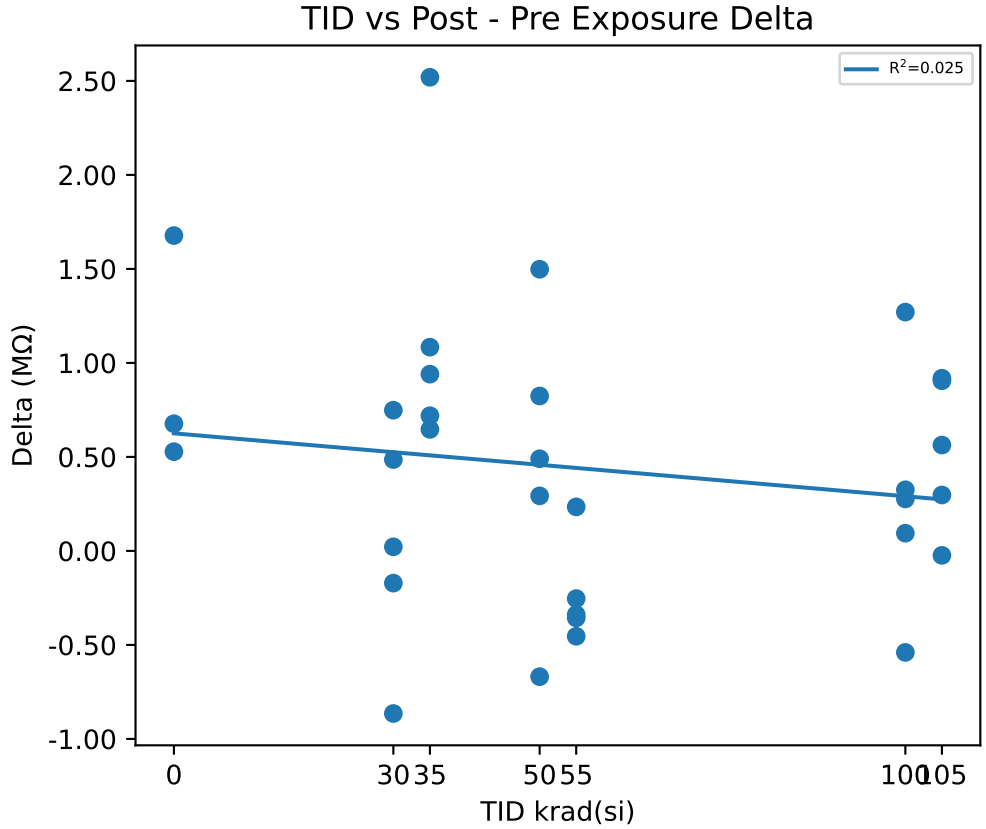
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	57.697	58.249	58.898	0.60663	58.721	58.929	59.131	0.20501	0.2328	0.68023	1.2377	0.51141
30	57.731	58.157	58.693	0.37791	58.317	58.616	59.168	0.32818	-0.3761	0.45858	1.2516	0.63429
35	57.691	58.464	58.973	0.59144	57.786	58.467	59.074	0.55732	-0.1324	0.00372	0.1228	0.10792
50	56.971	58.16	58.864	0.75716	58.785	59.111	59.465	0.27836	0.2572	0.95108	1.8132	0.62724
55	58.24	58.43	58.631	0.18117	58.675	59.294	59.989	0.5047	0.435	0.86394	1.3582	0.38908
100	57.648	58.4	59.2	0.55545	58.492	59.111	59.907	0.67108	-0.0019	0.71124	1.5069	0.54705
105	58.18	58.542	59.324	0.51001	58.075	58.588	59.796	0.71011	-0.9446	0.04622	1.5831	0.92855

Device Test: 50.2 _HsRdson|HighSide/SW2/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



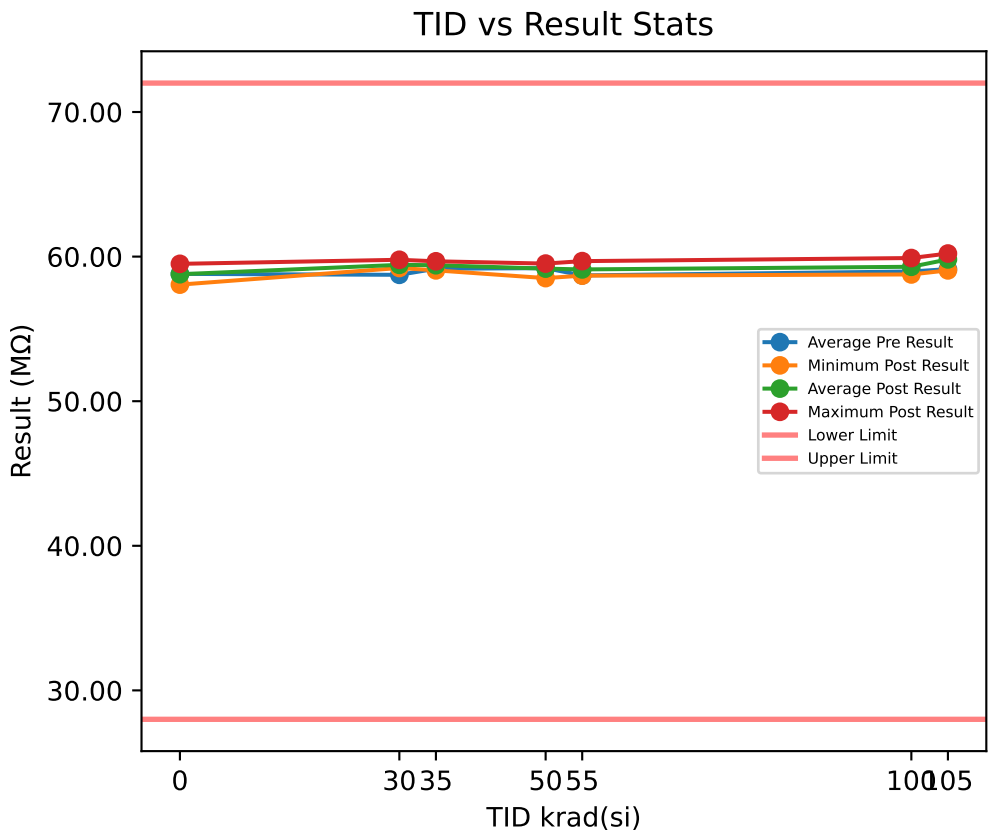
Test Results (Lower Limit = 28.0, Upper Limit = 72.0 (MΩ))

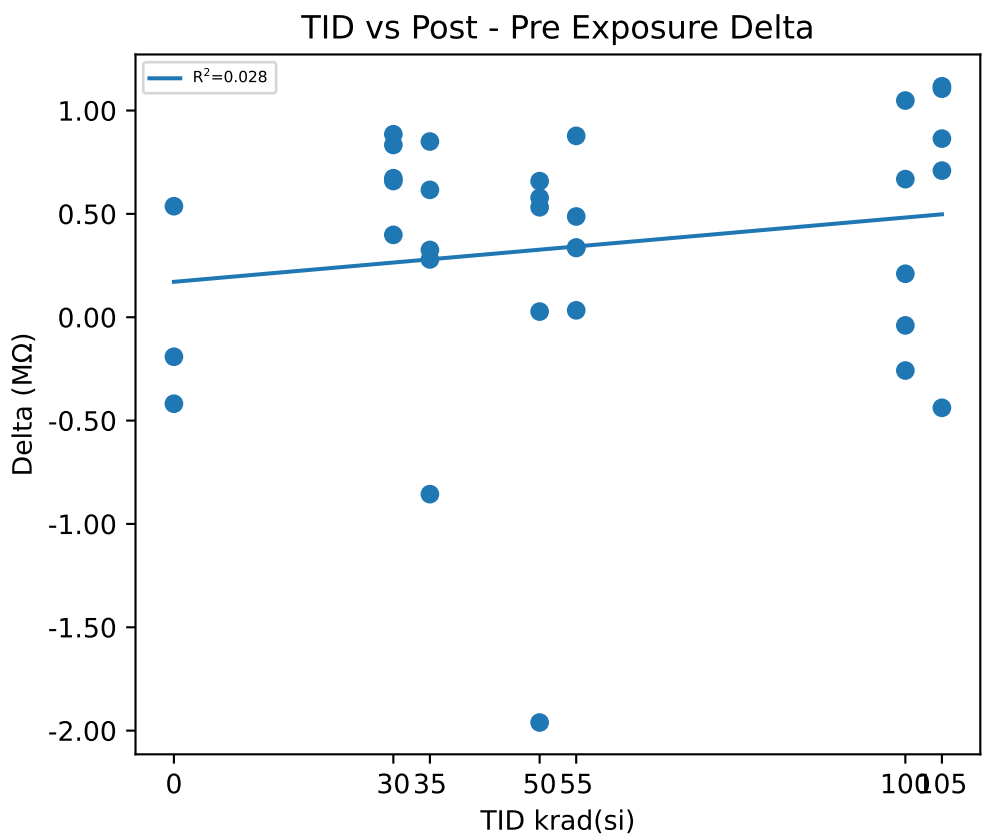
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	59.976	60.653	0.6766
2	0	CU2	59.923	60.451	0.5279
3	0	CU3	59.337	61.015	1.6775
11	30	Unbiased-30krad	59.344	60.093	0.7485
12	30	Unbiased-30krad	60.231	60.717	0.4861
13	30	Unbiased-30krad	60.121	59.256	-0.8648
14	30	Unbiased-30krad	60.233	60.062	-0.1713
15	30	Unbiased-30krad	60.225	60.247	0.0218
16	35	Biased-30krad	60.396	61.115	0.7192
17	35	Biased-30krad	58.758	59.842	1.0838
18	35	Biased-30krad	59.06	61.579	2.5193
19	35	Biased-30krad	60.079	61.019	0.9402
20	35	Biased-30krad	59.425	60.072	0.6466
30	50	Unbiased-50krad	59.726	60.55	0.8241
31	50	Unbiased-50krad	60.153	59.484	-0.6689
32	50	Unbiased-50krad	60.272	60.565	0.2929
33	50	Unbiased-50krad	59.921	60.411	0.4902
34	50	Unbiased-50krad	59.297	60.796	1.4984
40	55	Biased-50krad	60.053	60.288	0.2343
41	55	Biased-50krad	60.374	60.035	-0.3388
42	55	Biased-50krad	60.732	60.278	-0.454
43	55	Biased-50krad	60.076	59.719	-0.3562
44	55	Biased-50krad	59.742	59.489	-0.2536
45	100	Unbiased-100krad	59.559	59.836	0.2765
46	100	Unbiased-100krad	60.794	60.888	0.0943
47	100	Unbiased-100krad	60.651	60.111	-0.5399
48	100	Unbiased-100krad	60.001	60.326	0.3252
49	100	Unbiased-100krad	60.36	61.63	1.2703
50	105	Biased-100krad	60.575	60.873	0.2974
51	105	Biased-100krad	59.569	60.487	0.9186
52	105	Biased-100krad	59.918	60.823	0.9052
53	105	Biased-100krad	59.481	60.044	0.5632
54	105	Biased-100krad	60.195	60.172	-0.0237

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	59.337	59.746	59.976	0.3547	60.451	60.706	61.015	0.28547	0.5279	0.96067	1.6775	0.62523
30	59.344	60.031	60.233	0.38671	59.256	60.075	60.717	0.52729	-0.8648	0.04406	0.7485	0.62541
35	58.758	59.544	60.396	0.68512	59.842	60.725	61.579	0.73718	0.6466	1.1818	2.5193	0.76768
50	59.297	59.874	60.272	0.38509	59.484	60.361	60.796	0.50946	-0.6689	0.48734	1.4984	0.79221
55	59.742	60.196	60.732	0.37421	59.489	59.962	60.288	0.35164	-0.454	-0.23366	0.2343	0.27111
100	59.559	60.273	60.794	0.50138	59.836	60.558	61.63	0.71306	-0.5399	0.28528	1.2703	0.64987
105	59.481	59.948	60.575	0.45206	60.044	60.48	60.873	0.37313	-0.0237	0.53214	0.9186	0.40421

Device Test: 50.3 _HsRdson|HighSide/SW3/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C





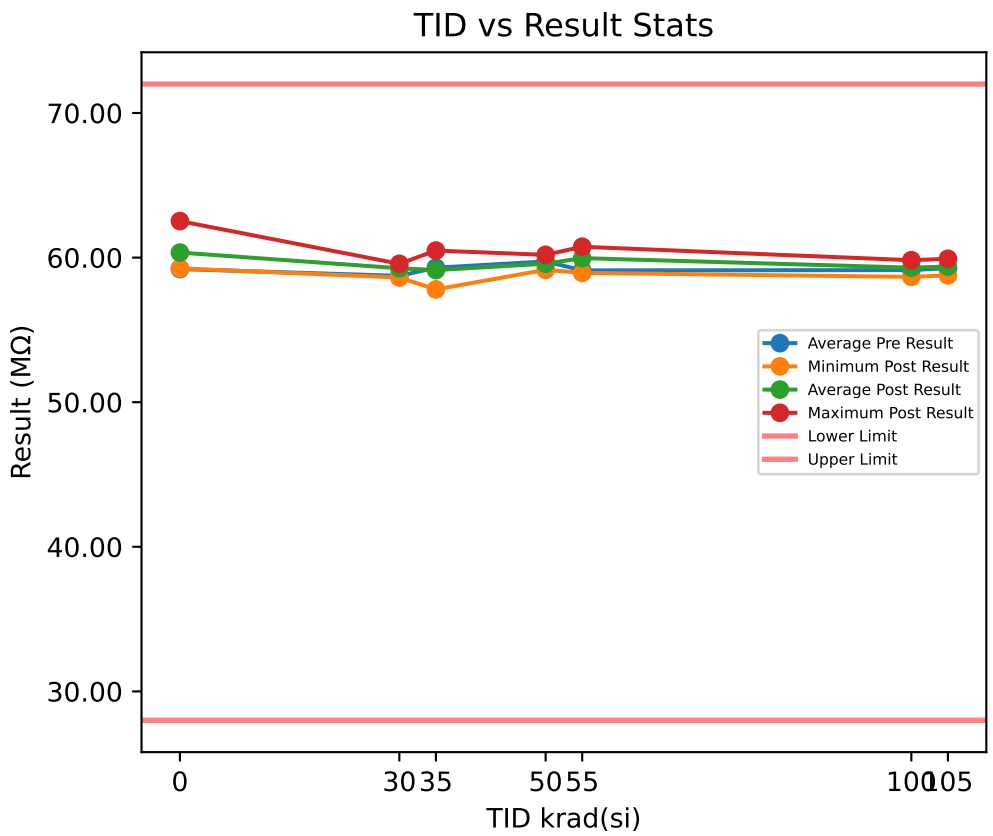
Test Results (Lower Limit = 28.0, Upper Limit = 72.0 (MΩ))

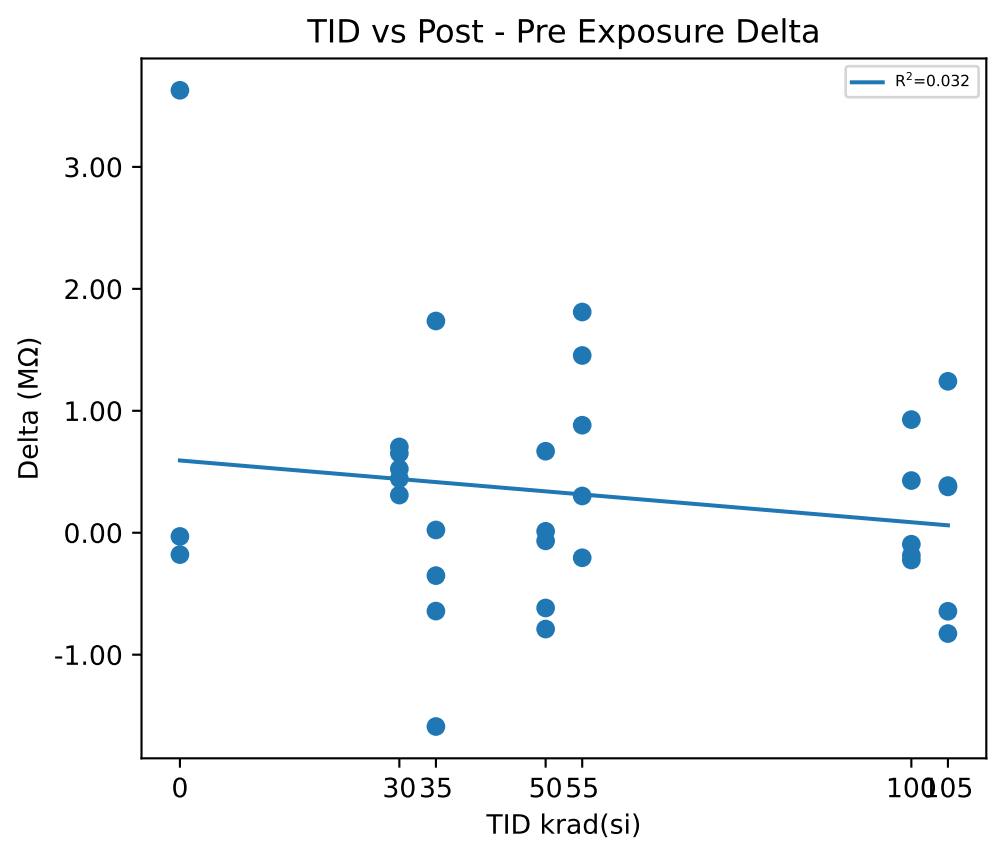
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	58.962	59.5	0.5371
2	0	CU2	58.48	58.061	-0.4184
3	0	CU3	58.972	58.781	-0.1912
11	30	Unbiased-30krad	58.503	59.337	0.8335
12	30	Unbiased-30krad	58.579	59.238	0.6589
13	30	Unbiased-30krad	58.327	59.213	0.8853
14	30	Unbiased-30krad	59.108	59.78	0.6727
15	30	Unbiased-30krad	59.184	59.583	0.3984
16	35	Biased-30krad	59.35	59.676	0.3255
17	35	Biased-30krad	60.342	59.486	-0.8559
18	35	Biased-30krad	58.768	59.048	0.2797
19	35	Biased-30krad	58.537	59.153	0.6162
20	35	Biased-30krad	58.807	59.657	0.8501
30	50	Unbiased-50krad	58.8	59.332	0.532
31	50	Unbiased-50krad	58.486	58.513	0.0274
32	50	Unbiased-50krad	58.813	59.471	0.6584
33	50	Unbiased-50krad	58.94	59.517	0.5779
34	50	Unbiased-50krad	60.97	59.01	-1.9607
40	55	Biased-50krad	58.898	58.931	0.0334
41	55	Biased-50krad	58.465	59.342	0.8774
42	55	Biased-50krad	58.348	58.683	0.3351
43	55	Biased-50krad	59.2	59.687	0.4874
44	55	Biased-50krad	58.587	58.925	0.3373
45	100	Unbiased-100krad	59.023	58.765	-0.2578
46	100	Unbiased-100krad	59.125	59.086	-0.0395
47	100	Unbiased-100krad	58.914	59.124	0.2103
48	100	Unbiased-100krad	58.936	59.604	0.6681
49	100	Unbiased-100krad	58.853	59.901	1.0484
50	105	Biased-100krad	59.348	60.213	0.8642
51	105	Biased-100krad	58.338	59.047	0.7094
52	105	Biased-100krad	60.224	59.786	-0.4382
53	105	Biased-100krad	58.765	59.882	1.1173
54	105	Biased-100krad	58.995	60.101	1.1056

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	58.48	58.805	58.972	0.28147	58.061	58.78	59.5	0.71915	-0.4184	-0.024167	0.5371	0.49917
30	58.327	58.74	59.184	0.38231	59.213	59.43	59.78	0.24431	0.3984	0.68976	0.8853	0.19041
35	58.537	59.161	60.342	0.7244	59.048	59.404	59.676	0.2892	-0.8559	0.24312	0.8501	0.65643
50	58.486	59.202	60.97	1.0028	58.513	59.169	59.517	0.41678	-1.9607	-0.033	0.6584	1.1057
55	58.348	58.7	59.2	0.34687	58.683	59.114	59.687	0.3987	0.0334	0.41412	0.8774	0.30704
100	58.853	58.97	59.125	0.10597	58.765	59.296	59.901	0.45174	-0.2578	0.3259	1.0484	0.53073
105	58.338	59.134	60.224	0.7111	59.047	59.806	60.213	0.45657	-0.4382	0.67166	1.1173	0.64366

Device Test: 50.4 _HsRdson|HighSide/SW4/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C





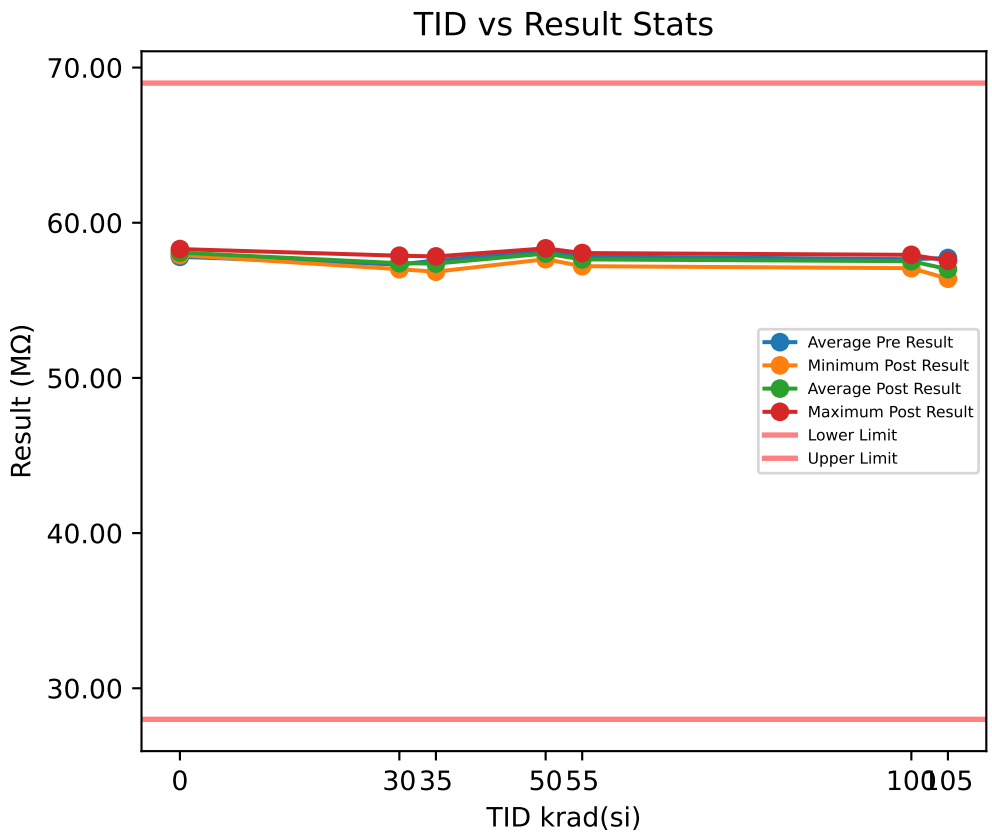
Test Results (Lower Limit = 28.0, Upper Limit = 72.0 (MΩ))

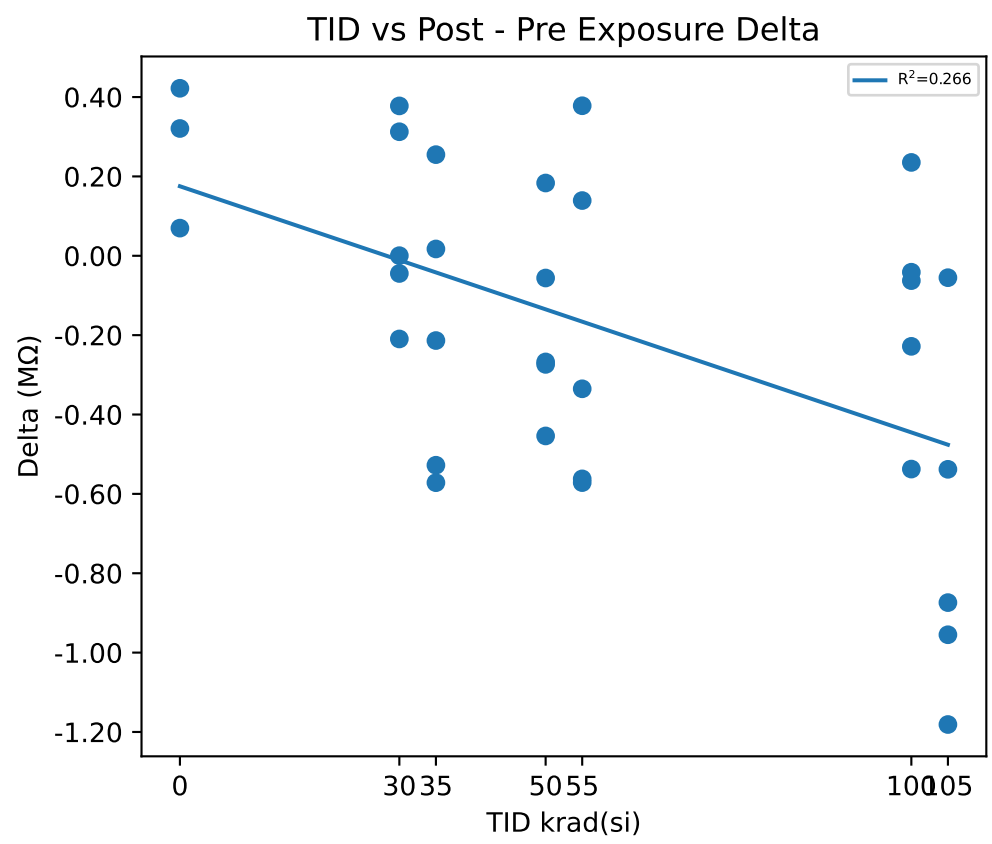
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	59.441	59.262	-0.1793
2	0	CU2	58.896	62.525	3.6283
3	0	CU3	59.286	59.256	-0.0303
11	30	Unbiased-30krad	58.804	59.455	0.6515
12	30	Unbiased-30krad	58.849	59.372	0.5231
13	30	Unbiased-30krad	58.314	58.623	0.3088
14	30	Unbiased-30krad	58.592	59.296	0.7038
15	30	Unbiased-30krad	59.127	59.571	0.4438
16	35	Biased-30krad	59.465	59.487	0.0228
17	35	Biased-30krad	58.751	60.487	1.7365
18	35	Biased-30krad	59.389	57.8	-1.5889
19	35	Biased-30krad	59.248	58.605	-0.6424
20	35	Biased-30krad	59.662	59.311	-0.3516
30	50	Unbiased-50krad	59.864	59.247	-0.6169
31	50	Unbiased-50krad	59.145	59.157	0.0119
32	50	Unbiased-50krad	60.264	59.475	-0.7896
33	50	Unbiased-50krad	59.521	60.19	0.6686
34	50	Unbiased-50krad	59.887	59.82	-0.0667
40	55	Biased-50krad	59.482	59.784	0.3016
41	55	Biased-50krad	59.147	58.942	-0.2052
42	55	Biased-50krad	58.915	60.725	1.8101
43	55	Biased-50krad	59.298	60.751	1.4537
44	55	Biased-50krad	58.738	59.62	0.8819
45	100	Unbiased-100krad	58.737	59.665	0.9278
46	100	Unbiased-100krad	60.044	59.821	-0.2238
47	100	Unbiased-100krad	58.95	59.378	0.4279
48	100	Unbiased-100krad	58.761	58.667	-0.0941
49	100	Unbiased-100krad	59.181	58.996	-0.1847
50	105	Biased-100krad	59.896	59.252	-0.6439
51	105	Biased-100krad	58.682	59.058	0.376
52	105	Biased-100krad	58.675	59.917	1.2419
53	105	Biased-100krad	59.598	58.771	-0.8266
54	105	Biased-100krad	59.53	59.917	0.3868

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	58.896	59.208	59.441	0.28085	59.256	60.348	62.525	1.8853	-0.1793	1.1396	3.6283	2.1566
30	58.314	58.737	59.127	0.30371	58.623	59.263	59.571	0.3723	0.3088	0.5262	0.7038	0.15914
35	58.751	59.303	59.662	0.34313	57.8	59.138	60.487	1.0057	-1.5889	-0.16472	1.7365	1.2187
50	59.145	59.736	60.264	0.42229	59.157	59.578	60.19	0.42734	-0.7896	-0.15854	0.6686	0.57662
55	58.738	59.116	59.482	0.29643	58.942	59.964	60.751	0.77381	-0.2052	0.84842	1.8101	0.8218
100	58.737	59.135	60.044	0.53891	58.667	59.305	59.821	0.47508	-0.2238	0.17062	0.9278	0.49785
105	58.675	59.276	59.896	0.5628	58.771	59.383	59.917	0.51663	-0.8266	0.10684	1.2419	0.84766

Device Test: 51.1 _LsRdson|LowSide/SW1/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C





Test Results (Lower Limit = 28.0, Upper Limit = 69.0 (MΩ))

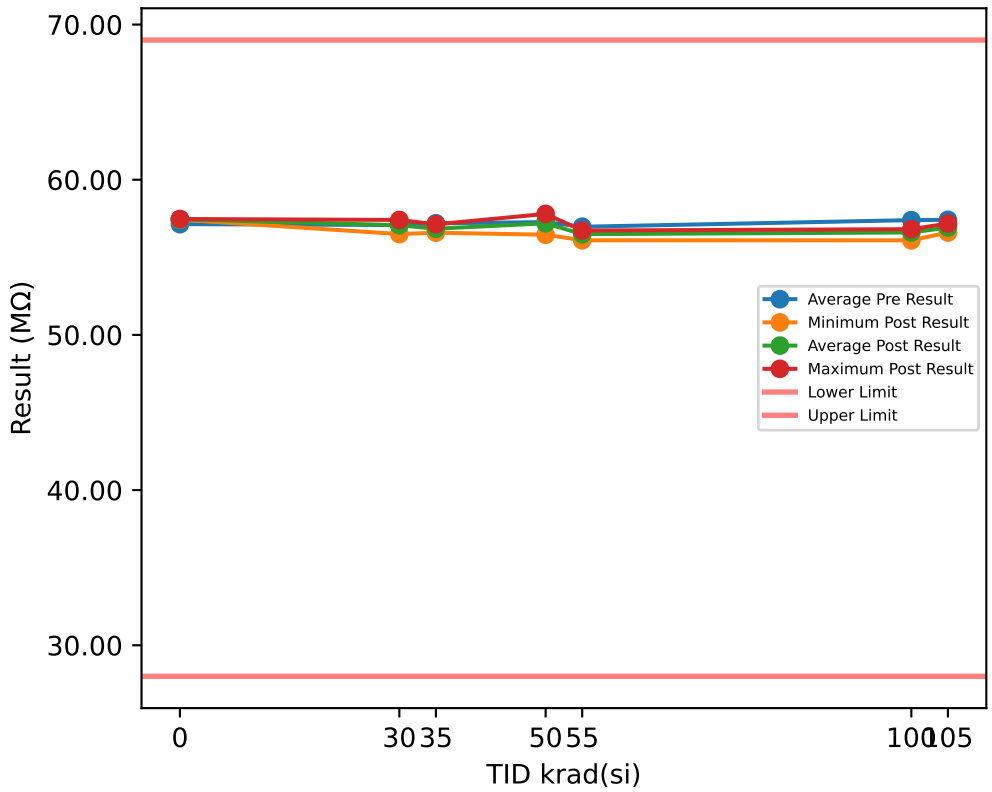
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	57.596	57.917	0.3208
2	0	CU2	57.882	58.304	0.4221
3	0	CU3	57.931	58.001	0.0697
11	30	Unbiased-30krad	57.043	57.356	0.3126
12	30	Unbiased-30krad	57.565	57.356	-0.2096
13	30	Unbiased-30krad	57.004	57.005	0.0003
14	30	Unbiased-30krad	57.419	57.375	-0.0446
15	30	Unbiased-30krad	57.498	57.876	0.3777
16	35	Biased-30krad	57.575	57.83	0.2549
17	35	Biased-30krad	57.31	57.328	0.0172
18	35	Biased-30krad	57.668	57.14	-0.5278
19	35	Biased-30krad	57.905	57.691	-0.2136
20	35	Biased-30krad	57.417	56.846	-0.5718
30	50	Unbiased-50krad	58.148	57.874	-0.2737
31	50	Unbiased-50krad	58.13	58.314	0.1834
32	50	Unbiased-50krad	58.617	58.35	-0.2675
33	50	Unbiased-50krad	58.104	57.65	-0.454
34	50	Unbiased-50krad	57.947	57.891	-0.056
40	55	Biased-50krad	57.944	57.372	-0.5716
41	55	Biased-50krad	57.902	57.567	-0.3352
42	55	Biased-50krad	57.67	58.048	0.3781
43	55	Biased-50krad	57.862	58.001	0.1392
44	55	Biased-50krad	57.763	57.2	-0.5622
45	100	Unbiased-100krad	57.406	57.365	-0.0414
46	100	Unbiased-100krad	58.16	57.932	-0.2282
47	100	Unbiased-100krad	57.61	57.072	-0.5375
48	100	Unbiased-100krad	57.754	57.692	-0.0626
49	100	Unbiased-100krad	57.322	57.557	0.2353
50	105	Biased-100krad	57.687	57.149	-0.5381
51	105	Biased-100krad	57.351	56.396	-0.955
52	105	Biased-100krad	57.934	57.06	-0.874
53	105	Biased-100krad	58.053	56.872	-1.1812
54	105	Biased-100krad	57.611	57.555	-0.0552

Test Statistics (MΩ)

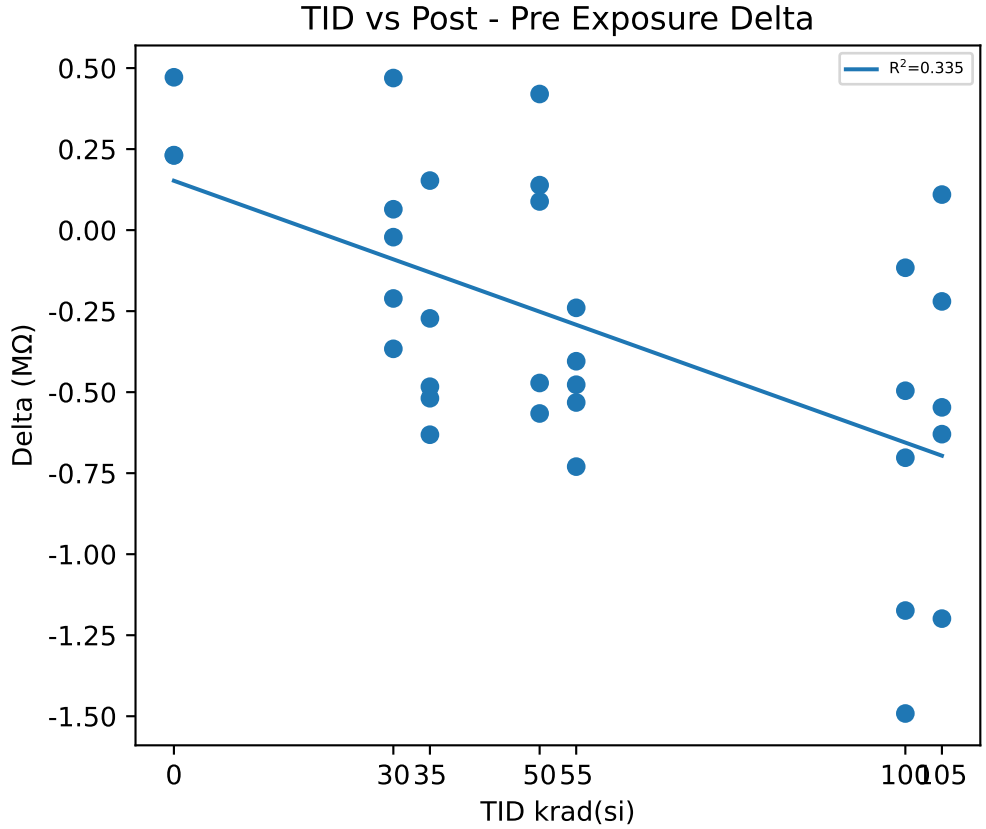
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	57.596	57.803	57.931	0.1808	57.917	58.074	58.304	0.20328	0.0697	0.27087	0.4221	0.18143
30	57.004	57.306	57.565	0.26324	57.005	57.393	57.876	0.31108	-0.2096	0.08728	0.3777	0.2491
35	57.31	57.575	57.905	0.23034	56.846	57.367	57.83	0.40127	-0.5718	-0.20822	0.2549	0.35343
50	57.947	58.189	58.617	0.25226	57.65	58.016	58.35	0.30405	-0.454	-0.17356	0.1834	0.24431
55	57.67	57.828	57.944	0.11086	57.2	57.638	58.048	0.37661	-0.5716	-0.19034	0.3781	0.42905
100	57.322	57.65	58.16	0.33154	57.072	57.524	57.932	0.3259	-0.5375	-0.12688	0.2353	0.2835
105	57.351	57.727	58.053	0.27627	56.396	57.006	57.555	0.42282	-1.1812	-0.7207	-0.0552	0.4378

Device Test: 51.2 _LsRdson|LowSide/SW2/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



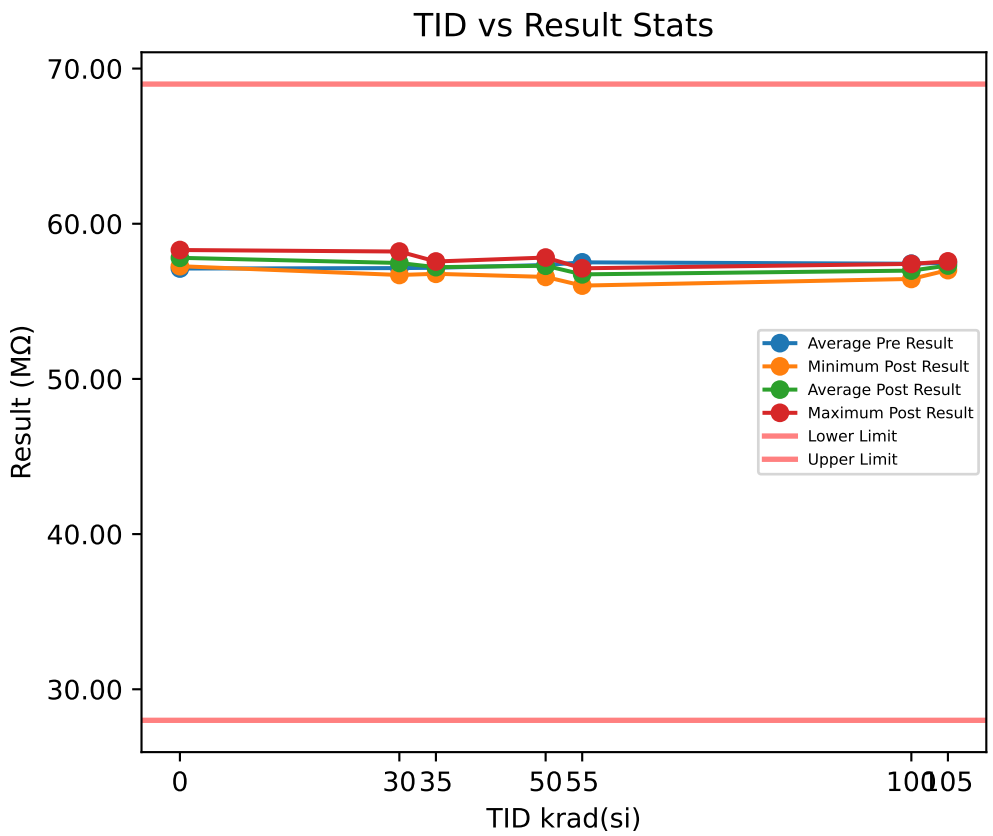
Test Results (Lower Limit = 28.0, Upper Limit = 69.0 (MΩ))

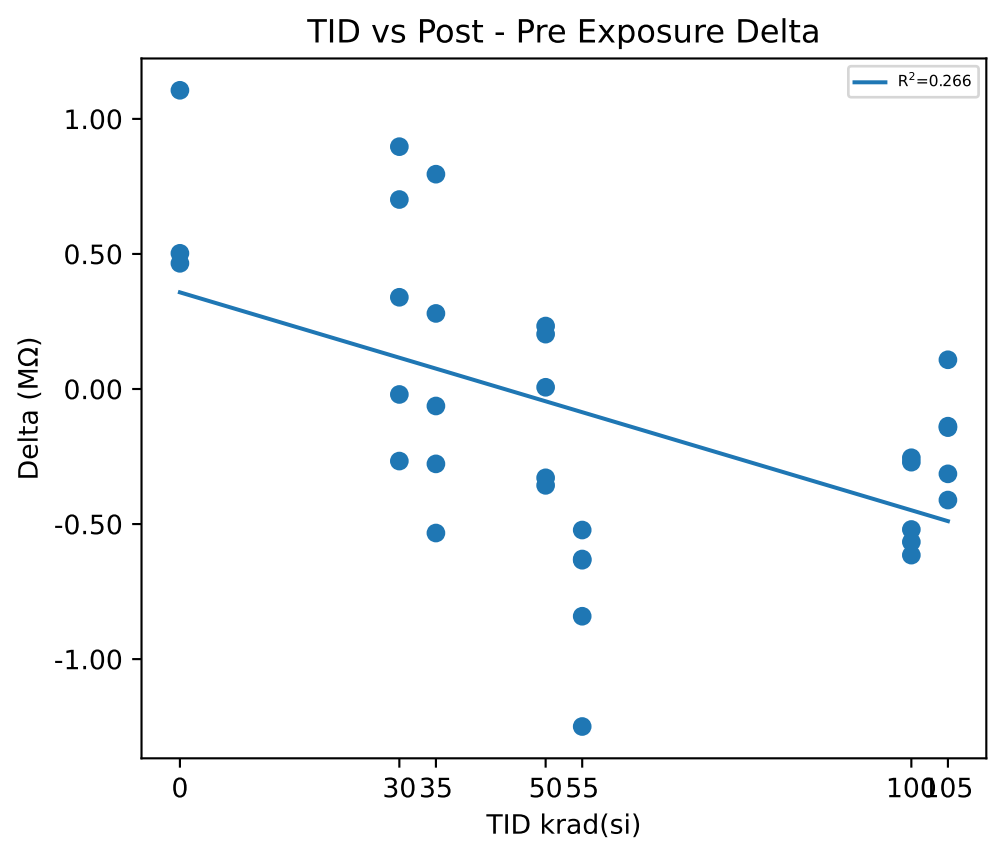
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	57.24	57.472	0.2314
2	0	CU2	57.199	57.43	0.2304
3	0	CU3	56.977	57.449	0.4716
11	30	Unbiased-30krad	56.635	57.105	0.4693
12	30	Unbiased-30krad	57.345	57.41	0.0644
13	30	Unbiased-30krad	56.71	56.499	-0.2109
14	30	Unbiased-30krad	56.986	56.964	-0.0217
15	30	Unbiased-30krad	57.731	57.365	-0.3663
16	35	Biased-30krad	57.662	57.031	-0.6313
17	35	Biased-30krad	57.106	56.587	-0.5188
18	35	Biased-30krad	57.399	57.126	-0.2724
19	35	Biased-30krad	57.203	56.72	-0.4832
20	35	Biased-30krad	56.603	56.756	0.1529
30	50	Unbiased-50krad	57.17	57.258	0.0884
31	50	Unbiased-50krad	57.023	56.457	-0.5658
32	50	Unbiased-50krad	57.425	56.953	-0.4717
33	50	Unbiased-50krad	57.357	57.496	0.1388
34	50	Unbiased-50krad	57.381	57.801	0.42
40	55	Biased-50krad	57.204	56.727	-0.477
41	55	Biased-50krad	56.916	56.511	-0.4046
42	55	Biased-50krad	57.243	56.711	-0.5319
43	55	Biased-50krad	57.155	56.425	-0.7298
44	55	Biased-50krad	56.34	56.1	-0.2398
45	100	Unbiased-100krad	57.271	56.097	-1.1739
46	100	Unbiased-100krad	58.249	56.757	-1.4916
47	100	Unbiased-100krad	57.311	56.816	-0.4956
48	100	Unbiased-100krad	56.728	56.612	-0.1161
49	100	Unbiased-100krad	57.429	56.726	-0.7023
50	105	Biased-100krad	57.797	56.598	-1.1988
51	105	Biased-100krad	56.736	56.845	0.1097
52	105	Biased-100krad	57.805	57.175	-0.6296
53	105	Biased-100krad	57.289	57.069	-0.22
54	105	Biased-100krad	57.453	56.906	-0.5469

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	56.977	57.139	57.24	0.14175	57.43	57.45	57.472	0.02099	0.2304	0.31113	0.4716	0.13897
30	56.635	57.081	57.731	0.45761	56.499	57.068	57.41	0.36758	-0.3663	-0.01304	0.4693	0.31728
35	56.603	57.195	57.662	0.39305	56.587	56.844	57.126	0.22568	-0.6313	-0.35056	0.1529	0.30996
50	57.023	57.271	57.425	0.16944	56.457	57.193	57.801	0.51584	-0.5658	-0.07806	0.42	0.42298
55	56.34	56.971	57.243	0.37555	56.1	56.495	56.727	0.25598	-0.7298	-0.47662	-0.2398	0.17918
100	56.728	57.397	58.249	0.54726	56.097	56.602	56.816	0.29169	-1.4916	-0.7959	-0.1161	0.54497
105	56.736	57.416	57.805	0.44064	56.598	56.919	57.175	0.22207	-1.1988	-0.49712	0.1097	0.48924

Device Test: 51.3 _LsRdson|LowSide/SW3/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C





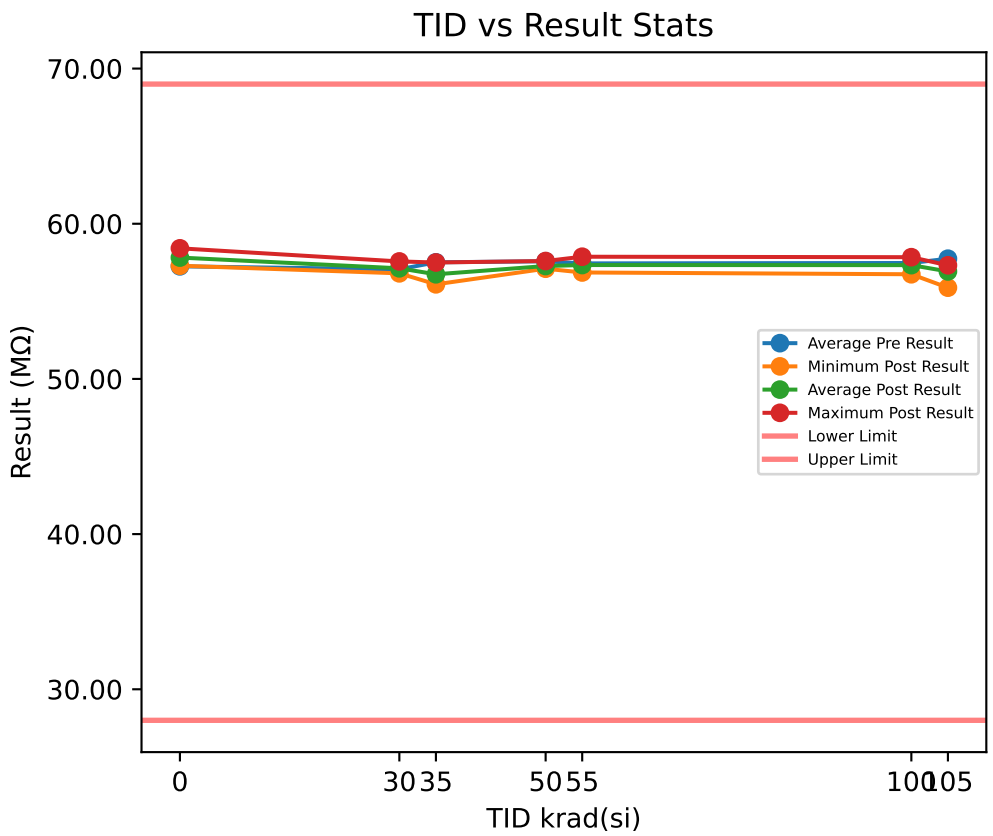
Test Results (Lower Limit = 28.0, Upper Limit = 69.0 (MΩ))

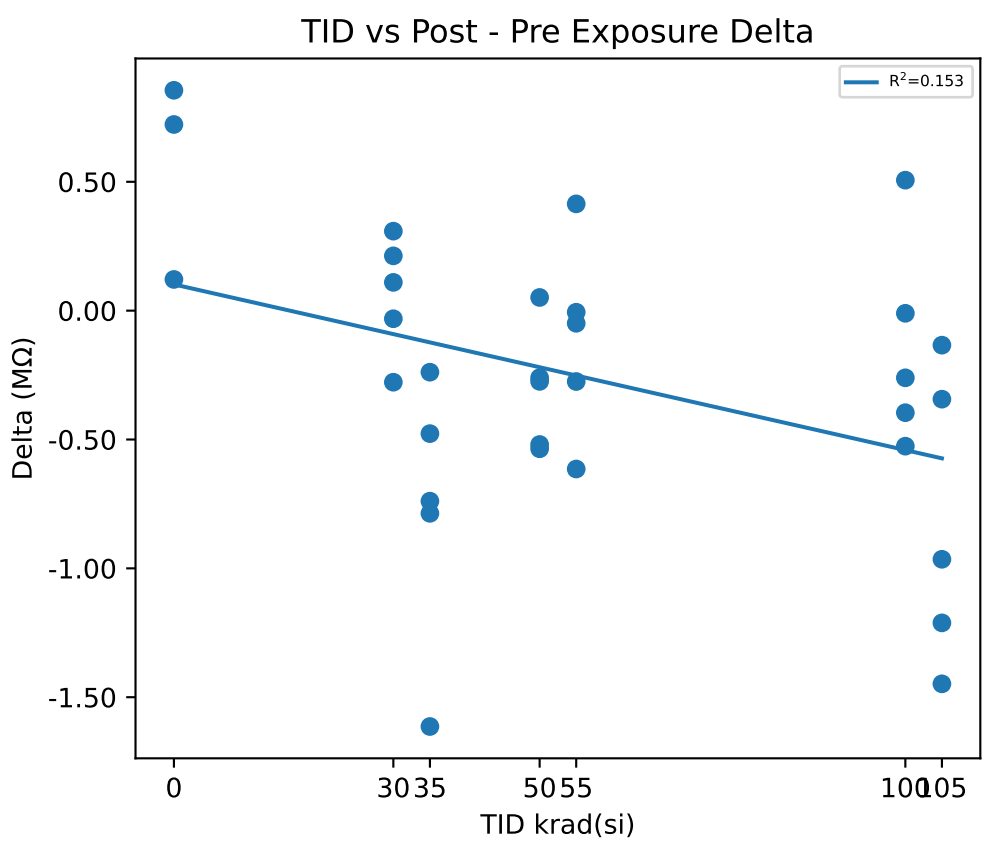
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	57.201	58.307	1.1059
2	0	CU2	56.799	57.264	0.4653
3	0	CU3	57.34	57.842	0.5024
11	30	Unbiased-30krad	56.799	57.501	0.7015
12	30	Unbiased-30krad	57.369	57.709	0.3396
13	30	Unbiased-30krad	56.965	56.698	-0.2668
14	30	Unbiased-30krad	57.263	57.243	-0.0202
15	30	Unbiased-30krad	57.312	58.209	0.8972
16	35	Biased-30krad	57.075	57.355	0.2798
17	35	Biased-30krad	57.144	56.867	-0.2772
18	35	Biased-30krad	57.631	57.568	-0.0629
19	35	Biased-30krad	57.307	56.774	-0.5332
20	35	Biased-30krad	56.651	57.447	0.7953
30	50	Unbiased-50krad	57.589	57.822	0.2331
31	50	Unbiased-50krad	56.901	56.573	-0.3288
32	50	Unbiased-50krad	57.392	57.399	0.0064
33	50	Unbiased-50krad	57.057	57.26	0.2031
34	50	Unbiased-50krad	57.766	57.41	-0.3567
40	55	Biased-50krad	57.651	57.129	-0.5221
41	55	Biased-50krad	57.339	56.709	-0.6294
42	55	Biased-50krad	57.623	56.989	-0.6339
43	55	Biased-50krad	57.69	56.848	-0.8413
44	55	Biased-50krad	57.264	56.014	-1.2495
45	100	Unbiased-100krad	57.008	56.442	-0.5662
46	100	Unbiased-100krad	57.63	57.375	-0.2545
47	100	Unbiased-100krad	57.291	56.676	-0.615
48	100	Unbiased-100krad	57.512	56.992	-0.5201
49	100	Unbiased-100krad	57.683	57.412	-0.2709
50	105	Biased-100krad	57.739	57.425	-0.3141
51	105	Biased-100krad	56.902	57.011	0.1082
52	105	Biased-100krad	57.713	57.575	-0.1376
53	105	Biased-100krad	57.5	57.089	-0.4111
54	105	Biased-100krad	57.573	57.43	-0.143

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	56.799	57.113	57.34	0.28119	57.264	57.804	58.307	0.52259	0.4653	0.6912	1.1059	0.35962
30	56.799	57.142	57.369	0.24708	56.698	57.472	58.209	0.55951	-0.2668	0.33026	0.8972	0.48441
35	56.651	57.162	57.631	0.35682	56.774	57.202	57.568	0.35801	-0.5332	0.04036	0.7953	0.51666
50	56.901	57.341	57.766	0.3602	56.573	57.293	57.822	0.45403	-0.3567	-0.04858	0.2331	0.28248
55	57.264	57.513	57.69	0.19666	56.014	56.738	57.129	0.43365	-1.2495	-0.77524	-0.5221	0.28923
100	57.008	57.425	57.683	0.27724	56.442	56.98	57.412	0.42559	-0.615	-0.44534	-0.2545	0.17017
105	56.902	57.485	57.739	0.34051	57.011	57.306	57.575	0.24309	-0.4111	-0.17952	0.1082	0.1985

Device Test: 51.4 _LsRdson|LowSide/SW4/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C





Test Results (Lower Limit = 28.0, Upper Limit = 69.0 (MΩ))

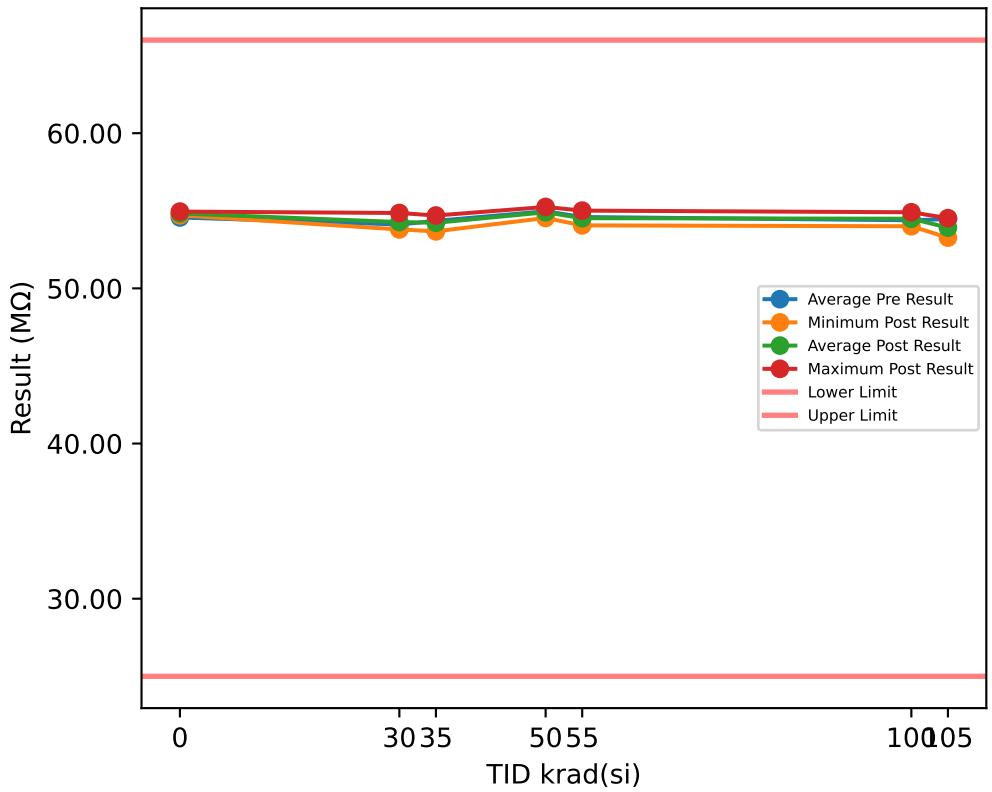
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	56.894	57.749	0.8551
2	0	CU2	57.694	58.416	0.7224
3	0	CU3	57.175	57.296	0.1211
11	30	Unbiased-30krad	56.964	56.933	-0.0314
12	30	Unbiased-30krad	57.263	57.572	0.3085
13	30	Unbiased-30krad	56.91	57.019	0.1097
14	30	Unbiased-30krad	57.102	57.314	0.2126
15	30	Unbiased-30krad	57.082	56.804	-0.2777
16	35	Biased-30krad	57.742	57.503	-0.2388
17	35	Biased-30krad	57.349	56.609	-0.7392
18	35	Biased-30krad	57.385	56.599	-0.7865
19	35	Biased-30krad	57.386	56.909	-0.4772
20	35	Biased-30krad	57.71	56.096	-1.6137
30	50	Unbiased-50krad	57.656	57.137	-0.5194
31	50	Unbiased-50krad	57.318	57.369	0.0512
32	50	Unbiased-50krad	57.858	57.598	-0.2601
33	50	Unbiased-50krad	57.638	57.102	-0.5359
34	50	Unbiased-50krad	57.441	57.167	-0.2745
40	55	Biased-50krad	57.135	56.86	-0.275
41	55	Biased-50krad	57.743	57.129	-0.6145
42	55	Biased-50krad	57.461	57.875	0.4143
43	55	Biased-50krad	57.537	57.531	-0.0061
44	55	Biased-50krad	57.35	57.301	-0.049
45	100	Unbiased-100krad	57.216	57.723	0.5064
46	100	Unbiased-100krad	57.855	57.845	-0.0103
47	100	Unbiased-100krad	57.141	56.745	-0.396
48	100	Unbiased-100krad	57.672	57.146	-0.5259
49	100	Unbiased-100krad	57.467	57.206	-0.2606
50	105	Biased-100krad	57.967	57.002	-0.9648
51	105	Biased-100krad	57.092	55.88	-1.2116
52	105	Biased-100krad	57.438	57.304	-0.1339
53	105	Biased-100krad	58.574	57.126	-1.4481
54	105	Biased-100krad	57.665	57.321	-0.3435

Test Statistics (MΩ)

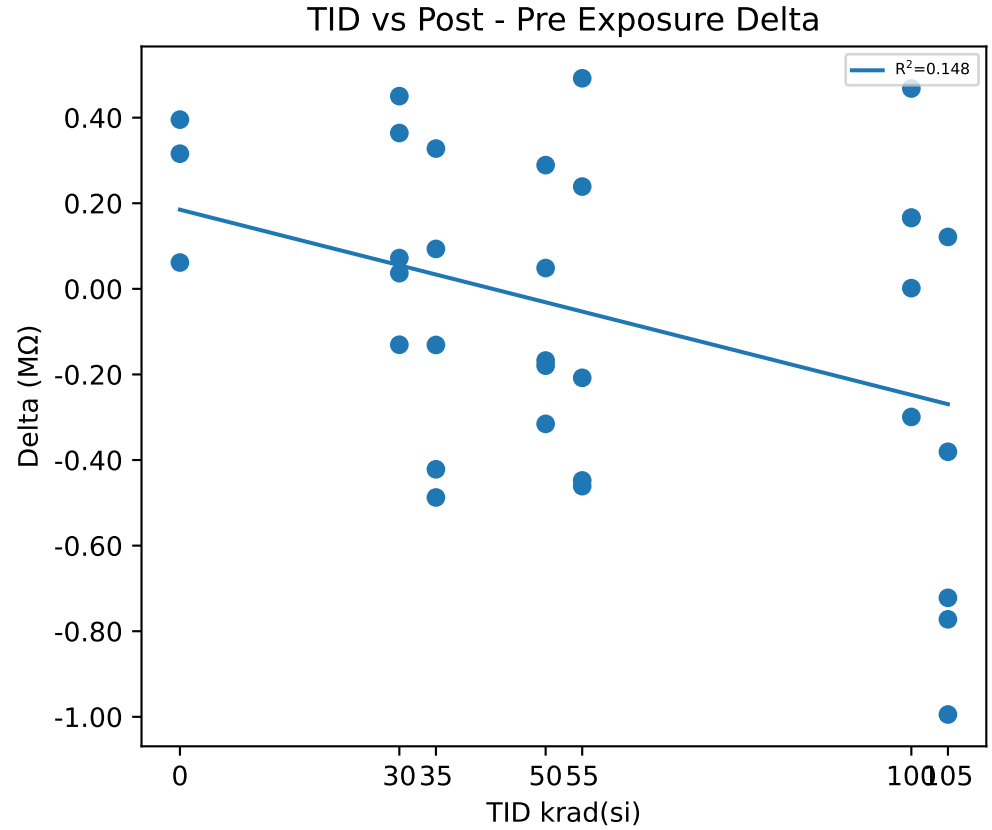
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	56.894	57.254	57.694	0.40593	57.296	57.821	58.416	0.5637	0.1211	0.5662	0.8551	0.39114
30	56.91	57.064	57.263	0.13715	56.804	57.128	57.572	0.31088	-0.2777	0.06434	0.3085	0.22903
35	57.349	57.514	57.742	0.19408	56.096	56.743	57.503	0.51524	-1.6137	-0.77108	-0.2388	0.51984
50	57.318	57.582	57.858	0.20866	57.102	57.275	57.598	0.20839	-0.5359	-0.30774	0.0512	0.23931
55	57.135	57.445	57.743	0.22528	56.86	57.339	57.875	0.38722	-0.6145	-0.10606	0.4143	0.37785
100	57.141	57.47	57.855	0.30082	56.745	57.333	57.845	0.45022	-0.5259	-0.13728	0.5064	0.40731
105	57.092	57.747	58.574	0.56209	55.88	56.927	57.321	0.59954	-1.4481	-0.82038	-0.1339	0.56272

Device Test: 52.1 _LsRdson|LowSide/SW1/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



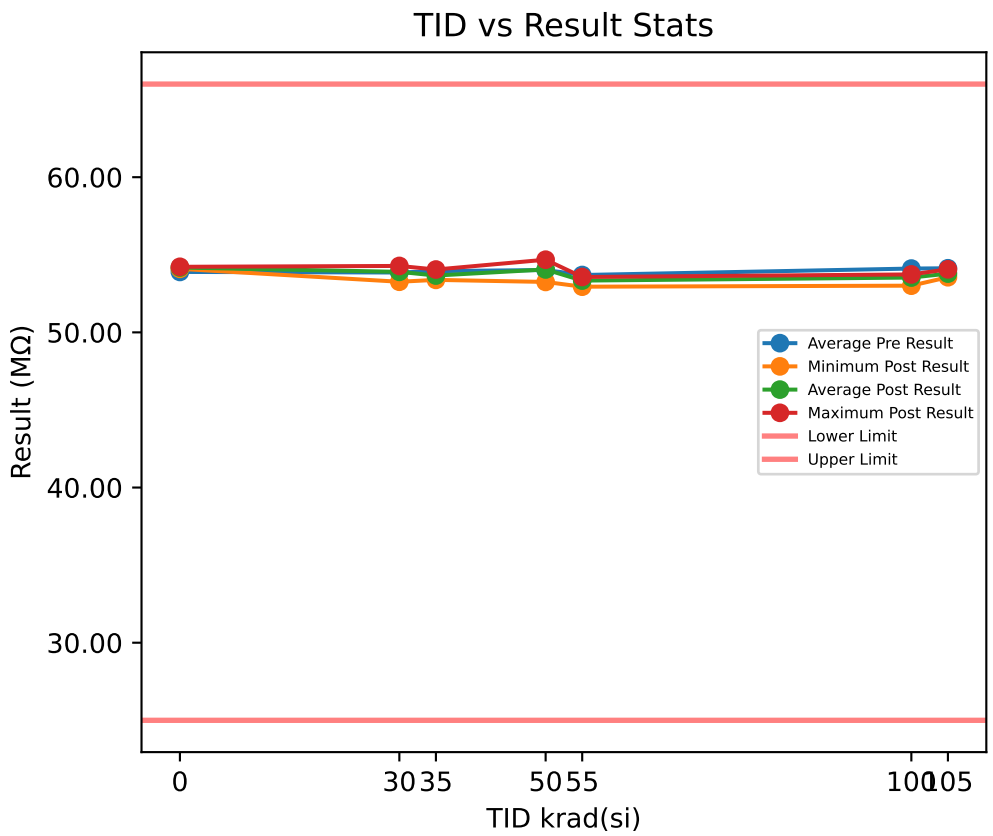
Test Results (Lower Limit = 25.0, Upper Limit = 66.0 (MΩ))

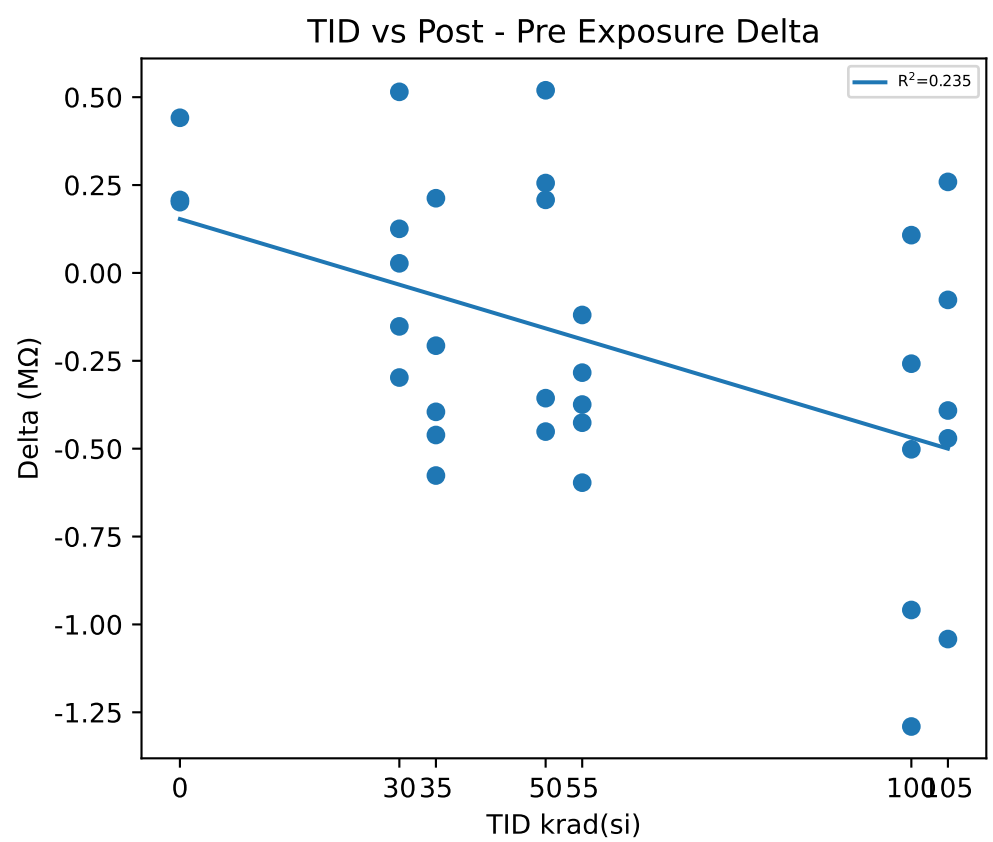
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	54.394	54.709	0.3158
2	0	CU2	54.553	54.948	0.3954
3	0	CU3	54.76	54.822	0.0615
11	30	Unbiased-30krad	53.826	54.191	0.3641
12	30	Unbiased-30krad	54.365	54.234	-0.1306
13	30	Unbiased-30krad	53.726	53.797	0.0719
14	30	Unbiased-30krad	54.254	54.291	0.0367
15	30	Unbiased-30krad	54.408	54.858	0.4503
16	35	Biased-30krad	54.367	54.695	0.3278
17	35	Biased-30krad	54.107	54.2	0.0933
18	35	Biased-30krad	54.506	54.084	-0.4216
19	35	Biased-30krad	54.607	54.476	-0.1311
20	35	Biased-30krad	54.162	53.675	-0.4875
30	50	Unbiased-50krad	54.924	54.756	-0.1675
31	50	Unbiased-50krad	54.829	55.118	0.2891
32	50	Unbiased-50krad	55.426	55.246	-0.1795
33	50	Unbiased-50krad	54.854	54.538	-0.3155
34	50	Unbiased-50krad	54.808	54.857	0.0486
40	55	Biased-50krad	54.651	54.19	-0.461
41	55	Biased-50krad	54.668	54.46	-0.2079
42	55	Biased-50krad	54.518	55.01	0.492
43	55	Biased-50krad	54.649	54.888	0.239
44	55	Biased-50krad	54.507	54.06	-0.4477
45	100	Unbiased-100krad	54.112	54.278	0.1655
46	100	Unbiased-100krad	54.903	54.904	0.0016
47	100	Unbiased-100krad	54.301	54.002	-0.2993
48	100	Unbiased-100krad	54.486	54.653	0.1666
49	100	Unbiased-100krad	54.135	54.603	0.4681
50	105	Biased-100krad	54.449	54.068	-0.3807
51	105	Biased-100krad	54.043	53.27	-0.7722
52	105	Biased-100krad	54.707	53.985	-0.722
53	105	Biased-100krad	54.718	53.724	-0.9946
54	105	Biased-100krad	54.403	54.525	0.1213

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54.394	54.569	54.76	0.18374	54.709	54.826	54.948	0.11932	0.0615	0.25757	0.3954	0.1744
30	53.726	54.116	54.408	0.31716	53.797	54.274	54.858	0.37978	-0.1306	0.15848	0.4503	0.24152
35	54.107	54.35	54.607	0.21482	53.675	54.226	54.695	0.38952	-0.4875	-0.12382	0.3278	0.34354
50	54.808	54.968	55.426	0.25945	54.538	54.903	55.246	0.28305	-0.3155	-0.06496	0.2891	0.23699
55	54.507	54.599	54.668	0.078932	54.06	54.522	55.01	0.41838	-0.461	-0.07712	0.492	0.42592
100	54.112	54.388	54.903	0.32481	54.002	54.488	54.904	0.35153	-0.2993	0.1005	0.4681	0.27989
105	54.043	54.464	54.718	0.27616	53.27	53.914	54.525	0.46156	-0.9946	-0.54964	0.1213	0.43472

Device Test: 52.2 _LsRdson|LowSide/SW2/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C





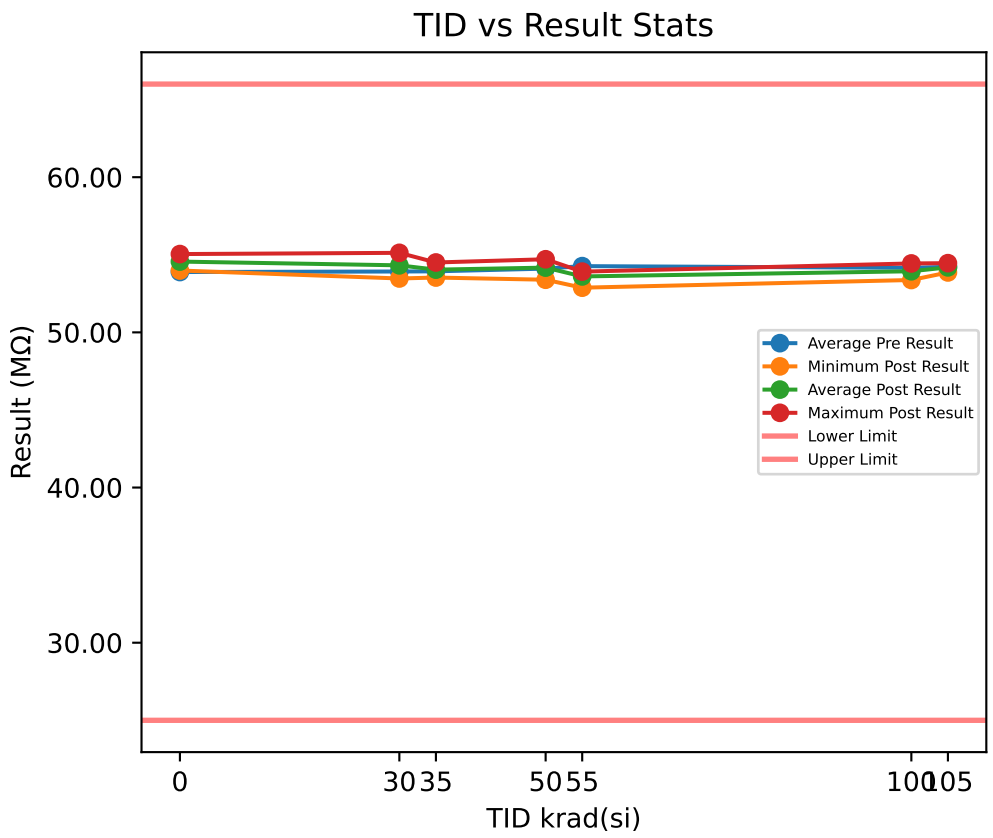
Test Results (Lower Limit = 25.0, Upper Limit = 66.0 (MΩ))

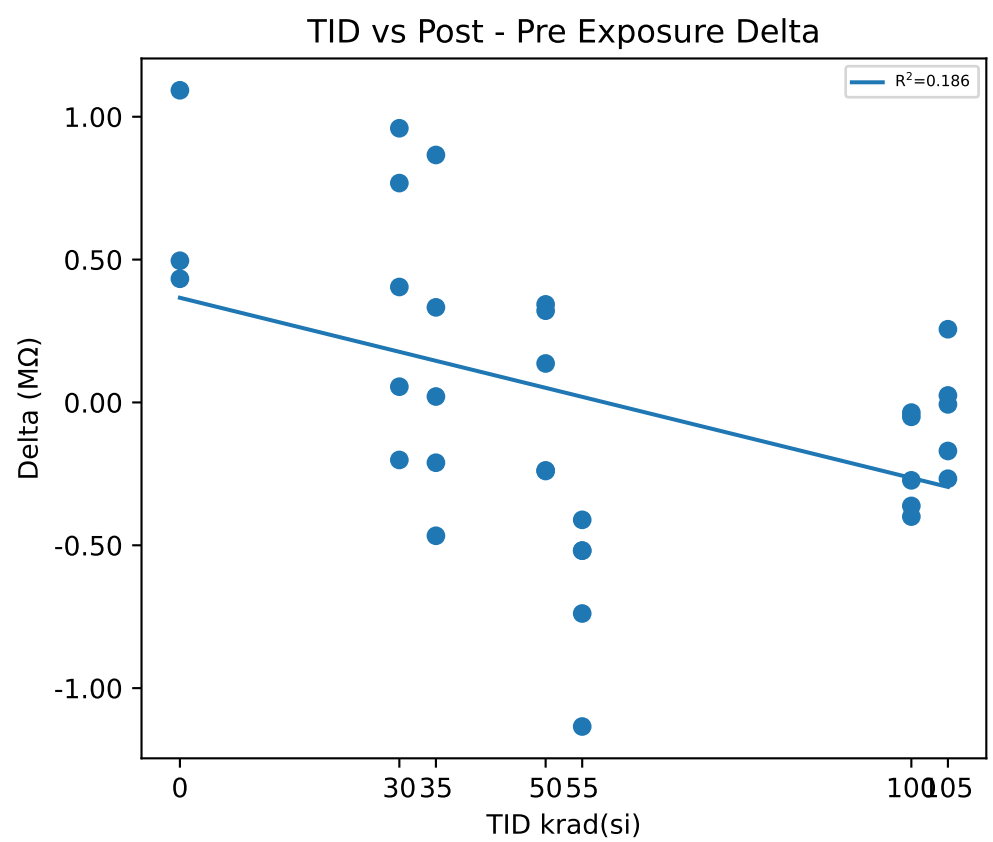
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	54.018	54.226	0.2077
2	0	CU2	53.892	54.093	0.2013
3	0	CU3	53.773	54.215	0.4414
11	30	Unbiased-30krad	53.355	53.87	0.5152
12	30	Unbiased-30krad	54.156	54.281	0.1255
13	30	Unbiased-30krad	53.414	53.262	-0.1521
14	30	Unbiased-30krad	53.789	53.816	0.0273
15	30	Unbiased-30krad	54.571	54.273	-0.2976
16	35	Biased-30krad	54.437	53.86	-0.5764
17	35	Biased-30krad	53.843	53.382	-0.4611
18	35	Biased-30krad	54.257	54.05	-0.207
19	35	Biased-30krad	53.871	53.476	-0.3952
20	35	Biased-30krad	53.329	53.541	0.2125
30	50	Unbiased-50krad	53.937	54.145	0.2079
31	50	Unbiased-50krad	53.702	53.25	-0.4514
32	50	Unbiased-50krad	54.208	53.851	-0.3563
33	50	Unbiased-50krad	54.082	54.337	0.2557
34	50	Unbiased-50krad	54.164	54.684	0.5196
40	55	Biased-50krad	53.865	53.491	-0.3744
41	55	Biased-50krad	53.602	53.318	-0.2837
42	55	Biased-50krad	53.995	53.569	-0.4261
43	55	Biased-50krad	53.958	53.361	-0.5967
44	55	Biased-50krad	53.063	52.944	-0.1196
45	100	Unbiased-100krad	53.968	53.009	-0.9589
46	100	Unbiased-100krad	54.968	53.678	-1.2904
47	100	Unbiased-100krad	53.975	53.717	-0.2582
48	100	Unbiased-100krad	53.413	53.52	0.1075
49	100	Unbiased-100krad	54.236	53.734	-0.5018
50	105	Biased-100krad	54.594	53.553	-1.0416
51	105	Biased-100krad	53.432	53.691	0.259
52	105	Biased-100krad	54.533	54.062	-0.4706
53	105	Biased-100krad	53.898	53.822	-0.0767
54	105	Biased-100krad	54.198	53.807	-0.3914

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.773	53.894	54.018	0.12232	54.093	54.178	54.226	0.073555	0.2013	0.28347	0.4414	0.13681
30	53.355	53.857	54.571	0.51274	53.262	53.9	54.281	0.41822	-0.2976	0.04366	0.5152	0.30988
35	53.329	53.947	54.437	0.4284	53.382	53.662	54.05	0.28152	-0.5764	-0.28544	0.2125	0.30889
50	53.702	54.018	54.208	0.20499	53.25	54.053	54.684	0.54132	-0.4514	0.0351	0.5196	0.41927
55	53.063	53.697	53.995	0.38602	52.944	53.337	53.569	0.24147	-0.5967	-0.3601	-0.1196	0.17622
100	53.413	54.112	54.968	0.56501	53.009	53.532	53.734	0.30417	-1.2904	-0.58036	0.1075	0.55465
105	53.432	54.131	54.594	0.48037	53.553	53.787	54.062	0.18815	-1.0416	-0.34426	0.259	0.48476

Device Test: 52.3 _LsRdson|LowSide/SW3/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C





Test Results (Lower Limit = 25.0, Upper Limit = 66.0 (MΩ))

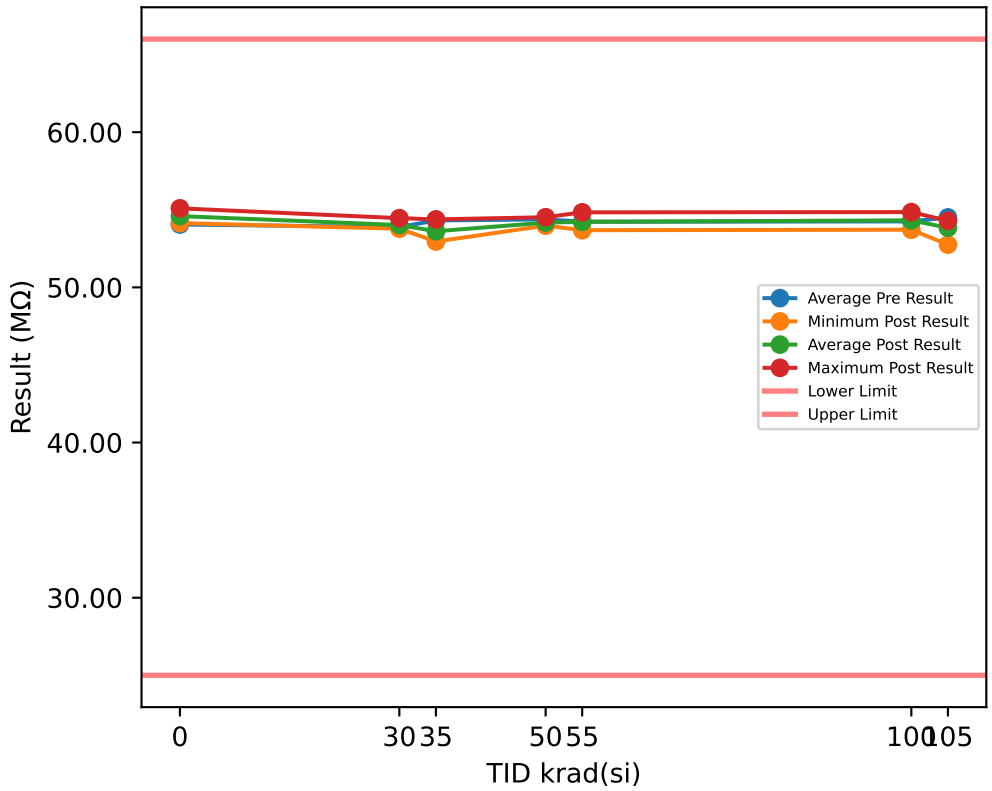
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	53.954	55.046	1.0926
2	0	CU2	53.553	53.986	0.4329
3	0	CU3	54.156	54.652	0.496
11	30	Unbiased-30krad	53.533	54.301	0.7678
12	30	Unbiased-30krad	54.167	54.571	0.4041
13	30	Unbiased-30krad	53.674	53.473	-0.2013
14	30	Unbiased-30krad	54.075	54.13	0.0551
15	30	Unbiased-30krad	54.166	55.125	0.9597
16	35	Biased-30krad	53.872	54.205	0.3328
17	35	Biased-30krad	53.911	53.7	-0.211
18	35	Biased-30krad	54.483	54.504	0.0207
19	35	Biased-30krad	54	53.533	-0.4667
20	35	Biased-30krad	53.404	54.27	0.8662
30	50	Unbiased-50krad	54.368	54.712	0.3432
31	50	Unbiased-50krad	53.63	53.392	-0.2379
32	50	Unbiased-50krad	54.198	54.334	0.1364
33	50	Unbiased-50krad	53.793	54.114	0.3211
34	50	Unbiased-50krad	54.554	54.314	-0.24
40	55	Biased-50krad	54.325	53.914	-0.4109
41	55	Biased-50krad	54.055	53.537	-0.5187
42	55	Biased-50krad	54.423	53.905	-0.5186
43	55	Biased-50krad	54.527	53.789	-0.7388
44	55	Biased-50krad	54.014	52.879	-1.1343
45	100	Unbiased-100krad	53.737	53.374	-0.3622
46	100	Unbiased-100krad	54.374	54.339	-0.0355
47	100	Unbiased-100krad	53.988	53.589	-0.3996
48	100	Unbiased-100krad	54.216	53.943	-0.2727
49	100	Unbiased-100krad	54.492	54.442	-0.0504
50	105	Biased-100krad	54.562	54.392	-0.1699
51	105	Biased-100krad	53.611	53.867	0.2563
52	105	Biased-100krad	54.467	54.46	-0.0068
53	105	Biased-100krad	54.128	53.861	-0.267
54	105	Biased-100krad	54.345	54.37	0.0245

Test Statistics (MΩ)

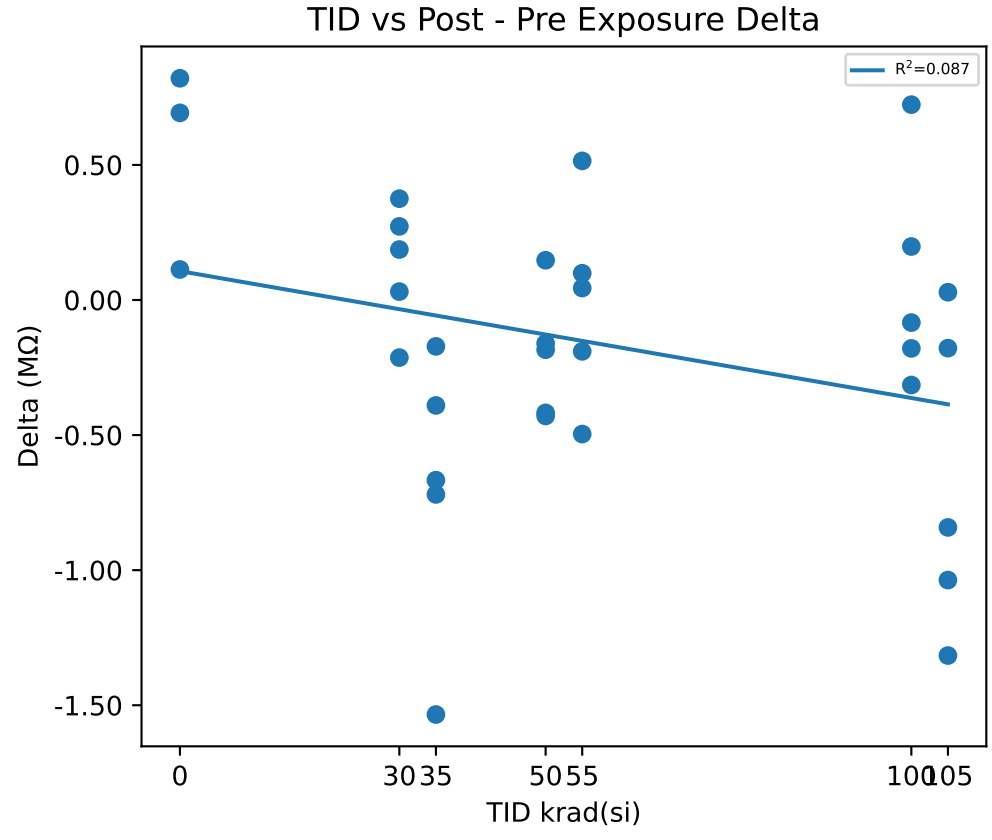
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.553	53.888	54.156	0.30687	53.986	54.562	55.046	0.53588	0.4329	0.67383	1.0926	0.36403
30	53.533	53.923	54.167	0.29823	53.473	54.32	55.125	0.60533	-0.2013	0.39708	0.9597	0.48193
35	53.404	53.934	54.483	0.38454	53.533	54.042	54.504	0.40867	-0.4667	0.1084	0.8662	0.51601
50	53.63	54.109	54.554	0.38828	53.392	54.173	54.712	0.48719	-0.24	0.06456	0.3432	0.28847
55	54.014	54.269	54.527	0.2262	52.879	53.605	53.914	0.43317	-1.1343	-0.66426	-0.4109	0.28857
100	53.737	54.161	54.492	0.3033	53.374	53.937	54.442	0.46203	-0.3996	-0.22408	-0.0355	0.17174
105	53.611	54.223	54.562	0.37827	53.861	54.19	54.46	0.2991	-0.267	-0.03258	0.2563	0.20074

Device Test: 52.4 _LsRdson|LowSide/SW4/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



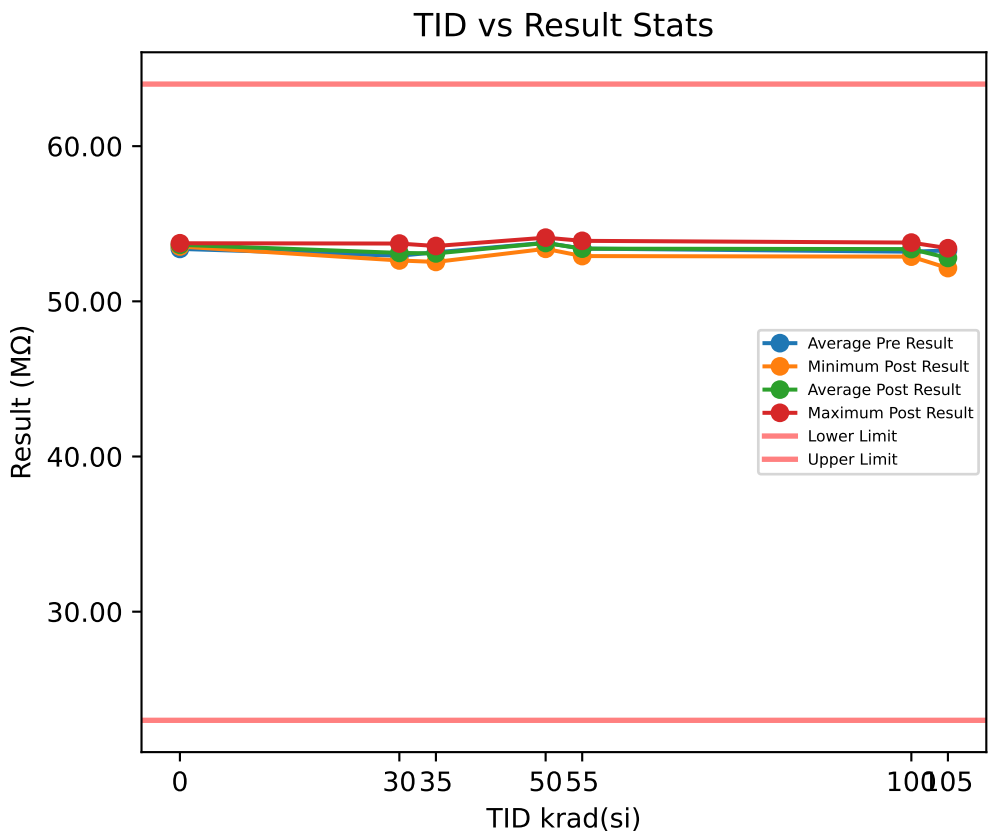
Test Results (Lower Limit = 25.0, Upper Limit = 66.0 (MΩ))

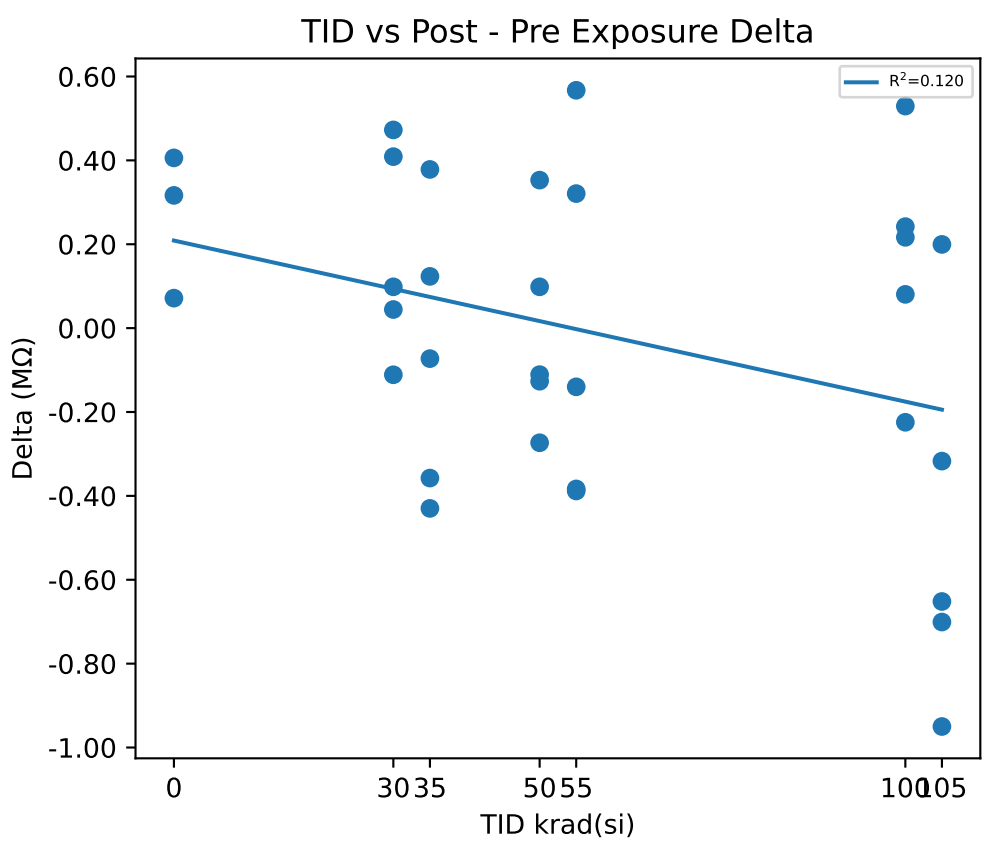
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	53.723	54.544	0.8207
2	0	CU2	54.401	55.093	0.6927
3	0	CU3	54.028	54.141	0.113
11	30	Unbiased-30krad	53.759	53.79	0.0311
12	30	Unbiased-30krad	54.086	54.461	0.3751
13	30	Unbiased-30krad	53.637	53.824	0.1869
14	30	Unbiased-30krad	53.952	54.225	0.2725
15	30	Unbiased-30krad	53.996	53.783	-0.2132
16	35	Biased-30krad	54.552	54.38	-0.1717
17	35	Biased-30krad	54.157	53.49	-0.6669
18	35	Biased-30krad	54.262	53.542	-0.7197
19	35	Biased-30krad	54.1	53.71	-0.3903
20	35	Biased-30krad	54.488	52.953	-1.5343
30	50	Unbiased-50krad	54.471	54.053	-0.4178
31	50	Unbiased-50krad	54.053	54.2	0.1471
32	50	Unbiased-50krad	54.681	54.52	-0.1605
33	50	Unbiased-50krad	54.408	53.978	-0.4291
34	50	Unbiased-50krad	54.296	54.112	-0.184
40	55	Biased-50krad	53.875	53.685	-0.1901
41	55	Biased-50krad	54.519	54.023	-0.4961
42	55	Biased-50krad	54.321	54.836	0.515
43	55	Biased-50krad	54.331	54.431	0.0991
44	55	Biased-50krad	54.101	54.145	0.0443
45	100	Unbiased-100krad	53.932	54.655	0.7231
46	100	Unbiased-100krad	54.652	54.85	0.198
47	100	Unbiased-100krad	53.894	53.714	-0.1791
48	100	Unbiased-100krad	54.445	54.13	-0.3146
49	100	Unbiased-100krad	54.327	54.244	-0.0836
50	105	Biased-100krad	54.768	53.927	-0.8417
51	105	Biased-100krad	53.789	52.752	-1.0367
52	105	Biased-100krad	54.233	54.262	0.0288
53	105	Biased-100krad	55.279	53.962	-1.316
54	105	Biased-100krad	54.469	54.291	-0.1782

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.723	54.05	54.401	0.33942	54.141	54.593	55.093	0.47823	0.113	0.54213	0.8207	0.37711
30	53.637	53.886	54.086	0.18349	53.783	54.017	54.461	0.30982	-0.2132	0.13048	0.3751	0.22977
35	54.1	54.312	54.552	0.1999	52.953	53.615	54.38	0.51312	-1.5343	-0.69658	-0.1717	0.51781
50	54.053	54.382	54.681	0.23077	53.978	54.173	54.52	0.21049	-0.4291	-0.20886	0.1471	0.23549
55	53.875	54.229	54.519	0.24752	53.685	54.224	54.836	0.43441	-0.4961	-0.00556	0.515	0.37387
100	53.894	54.25	54.652	0.32941	53.714	54.319	54.85	0.44773	-0.3146	0.06876	0.7231	0.41124
105	53.789	54.508	55.279	0.56028	52.752	53.839	54.291	0.62978	-1.316	-0.66876	0.0288	0.57259

Device Test: 53.1 _LsRdson|LowSide/SW1/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C





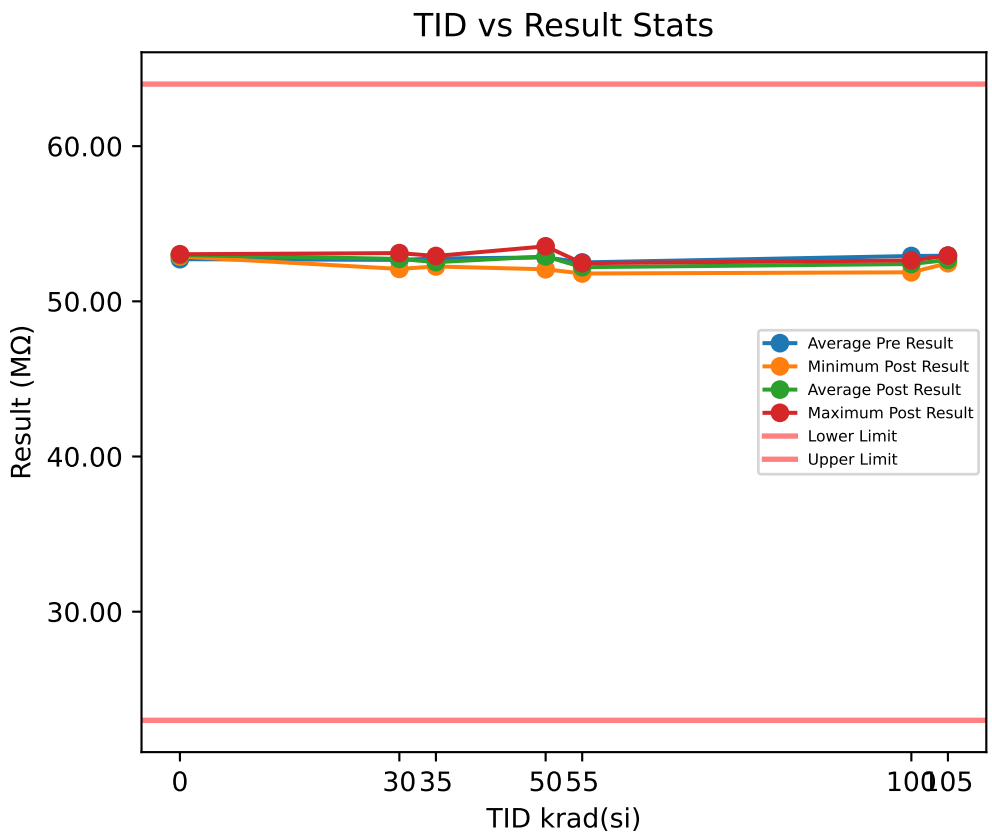
Test Results (Lower Limit = 23.0, Upper Limit = 64.0 (MΩ))

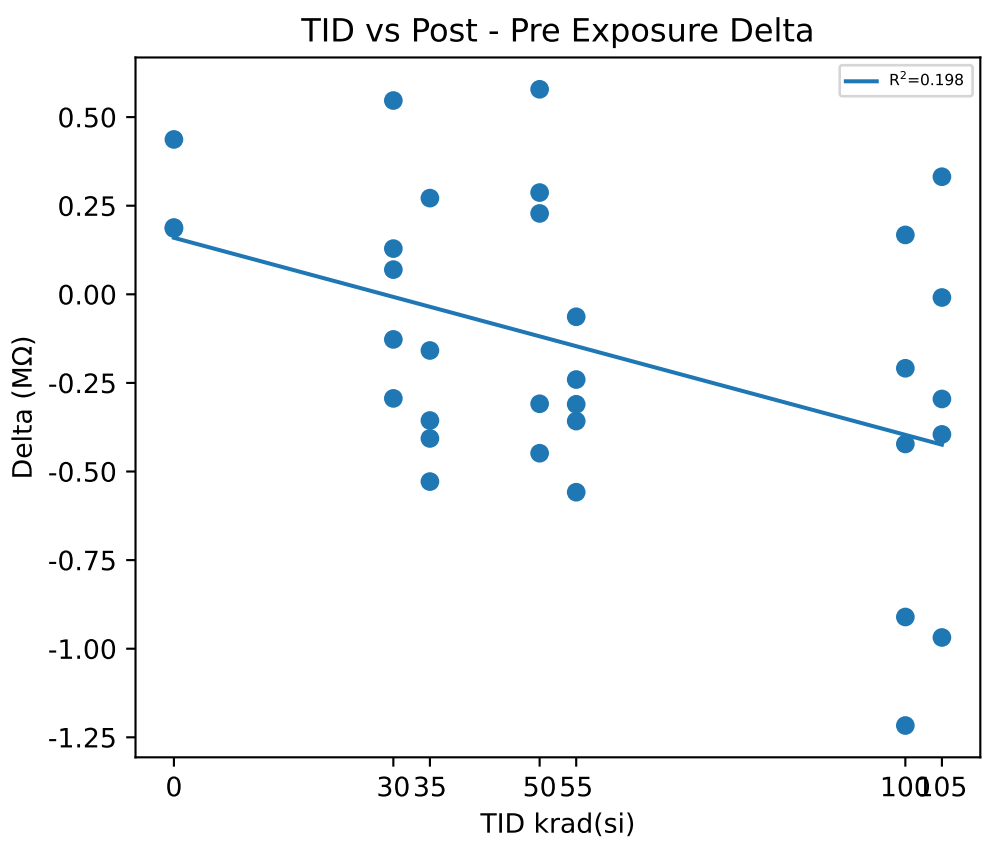
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	53.216	53.533	0.3165
2	0	CU2	53.337	53.743	0.4059
3	0	CU3	53.581	53.653	0.0715
11	30	Unbiased-30krad	52.635	53.044	0.4089
12	30	Unbiased-30krad	53.174	53.062	-0.1112
13	30	Unbiased-30krad	52.535	52.633	0.0985
14	30	Unbiased-30krad	53.096	53.14	0.0444
15	30	Unbiased-30krad	53.251	53.724	0.4726
16	35	Biased-30krad	53.187	53.566	0.3784
17	35	Biased-30krad	52.932	53.056	0.1234
18	35	Biased-30krad	53.319	52.961	-0.3575
19	35	Biased-30krad	53.391	53.319	-0.0727
20	35	Biased-30krad	52.969	52.539	-0.4298
30	50	Unbiased-50krad	53.726	53.615	-0.1109
31	50	Unbiased-50krad	53.618	53.971	0.3529
32	50	Unbiased-50krad	54.23	54.104	-0.1266
33	50	Unbiased-50krad	53.657	53.384	-0.2733
34	50	Unbiased-50krad	53.629	53.727	0.0985
40	55	Biased-50krad	53.436	53.052	-0.3834
41	55	Biased-50krad	53.478	53.338	-0.14
42	55	Biased-50krad	53.331	53.898	0.5671
43	55	Biased-50krad	53.448	53.769	0.3208
44	55	Biased-50krad	53.305	52.917	-0.3883
45	100	Unbiased-100krad	52.904	53.146	0.242
46	100	Unbiased-100krad	53.706	53.786	0.0805
47	100	Unbiased-100krad	53.105	52.88	-0.2245
48	100	Unbiased-100krad	53.302	53.518	0.2165
49	100	Unbiased-100krad	52.974	53.503	0.5294
50	105	Biased-100krad	53.279	52.962	-0.3171
51	105	Biased-100krad	52.844	52.143	-0.7008
52	105	Biased-100krad	53.53	52.878	-0.6518
53	105	Biased-100krad	53.528	52.578	-0.9499
54	105	Biased-100krad	53.223	53.422	0.1996

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.216	53.378	53.581	0.18598	53.533	53.643	53.743	0.10555	0.0715	0.26463	0.4059	0.17313
30	52.535	52.938	53.251	0.3289	52.633	53.121	53.724	0.39079	-0.1112	0.18264	0.4726	0.2489
35	52.932	53.16	53.391	0.20476	52.539	53.088	53.566	0.38718	-0.4298	-0.07164	0.3784	0.33562
50	53.618	53.772	54.23	0.25967	53.384	53.76	54.104	0.28564	-0.2733	-0.01188	0.3529	0.24318
55	53.305	53.4	53.478	0.076479	52.917	53.395	53.898	0.43066	-0.3883	-0.00476	0.5671	0.43063
100	52.904	53.198	53.706	0.32163	52.88	53.367	53.786	0.35454	-0.2245	0.16878	0.5294	0.27393
105	52.844	53.281	53.53	0.28164	52.143	52.797	53.422	0.47445	-0.9499	-0.484	0.1996	0.44367

Device Test: 53.2 _LsRdson|LowSide/SW2/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C





Test Results (Lower Limit = 23.0, Upper Limit = 64.0 (MΩ))

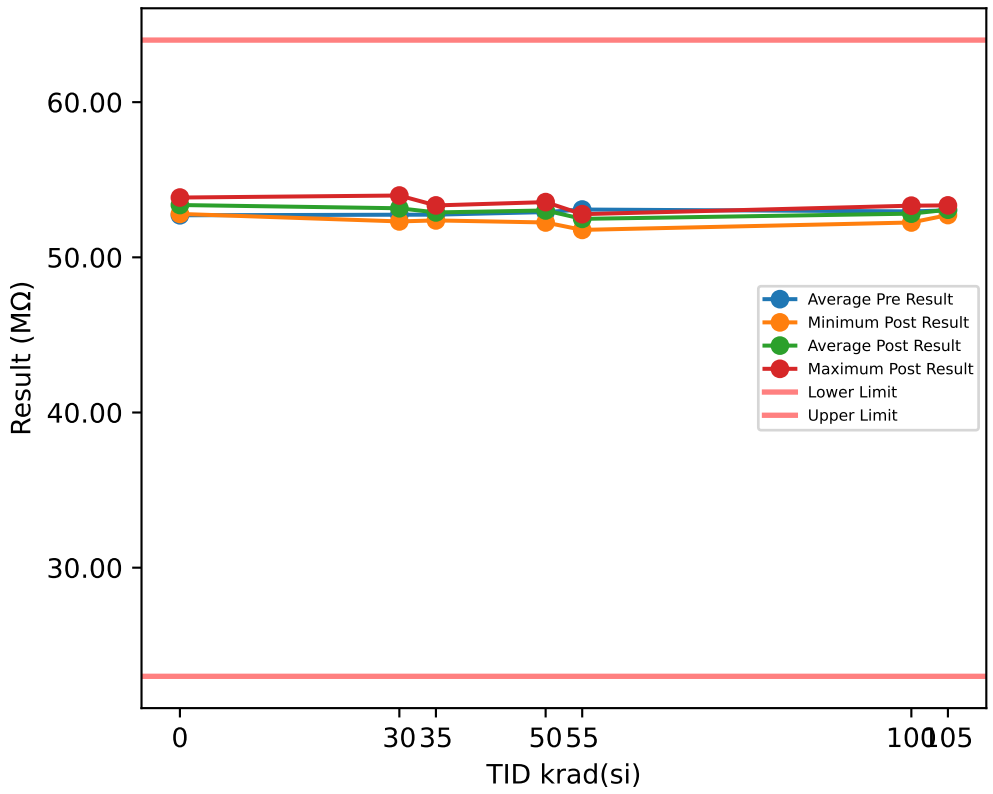
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	52.85	53.035	0.1856
2	0	CU2	52.702	52.89	0.1885
3	0	CU3	52.596	53.033	0.437
11	30	Unbiased-30krad	52.162	52.708	0.5468
12	30	Unbiased-30krad	52.969	53.098	0.129
13	30	Unbiased-30krad	52.216	52.089	-0.1273
14	30	Unbiased-30krad	52.604	52.674	0.0697
15	30	Unbiased-30krad	53.402	53.108	-0.2937
16	35	Biased-30krad	53.259	52.731	-0.5284
17	35	Biased-30krad	52.653	52.247	-0.4067
18	35	Biased-30krad	53.082	52.924	-0.1585
19	35	Biased-30krad	52.672	52.316	-0.3561
20	35	Biased-30krad	52.129	52.401	0.2714
30	50	Unbiased-50krad	52.761	52.989	0.2282
31	50	Unbiased-50krad	52.514	52.066	-0.4484
32	50	Unbiased-50krad	53.012	52.703	-0.3089
33	50	Unbiased-50krad	52.889	53.176	0.2871
34	50	Unbiased-50krad	52.968	53.546	0.5785
40	55	Biased-50krad	52.651	52.341	-0.3103
41	55	Biased-50krad	52.411	52.17	-0.2405
42	55	Biased-50krad	52.817	52.46	-0.3577
43	55	Biased-50krad	52.801	52.243	-0.5584
44	55	Biased-50krad	51.857	51.794	-0.0634
45	100	Unbiased-100krad	52.781	51.87	-0.9105
46	100	Unbiased-100krad	53.77	52.553	-1.2167
47	100	Unbiased-100krad	52.78	52.572	-0.2087
48	100	Unbiased-100krad	52.22	52.388	0.1676
49	100	Unbiased-100krad	53.056	52.634	-0.4223
50	105	Biased-100krad	53.424	52.456	-0.9683
51	105	Biased-100krad	52.225	52.557	0.3318
52	105	Biased-100krad	53.344	52.949	-0.3953
53	105	Biased-100krad	52.697	52.688	-0.009
54	105	Biased-100krad	53.01	52.715	-0.2953

Test Statistics (MΩ)

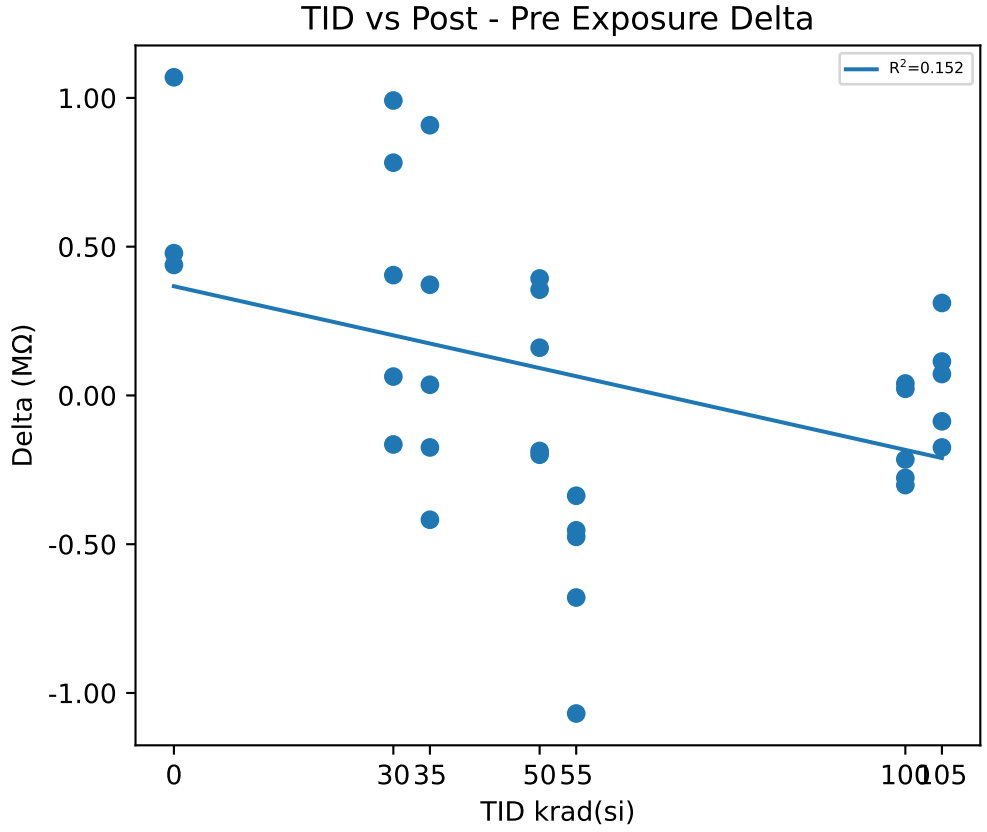
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.596	52.716	52.85	0.12768	52.89	52.986	53.035	0.083035	0.1856	0.27037	0.437	0.14432
30	52.162	52.671	53.402	0.52311	52.089	52.735	53.108	0.41645	-0.2937	0.0649	0.5468	0.31698
35	52.129	52.759	53.259	0.43866	52.247	52.524	52.924	0.29057	-0.5284	-0.23566	0.2714	0.31326
50	52.514	52.829	53.012	0.20027	52.066	52.896	53.546	0.55601	-0.4484	0.0673	0.5785	0.43099
55	51.857	52.508	52.817	0.39865	51.794	52.202	52.46	0.25265	-0.5584	-0.30606	-0.0634	0.17996
100	52.22	52.922	53.77	0.56337	51.87	52.403	52.634	0.31146	-1.2167	-0.51812	0.1676	0.55161
105	52.225	52.94	53.424	0.4931	52.456	52.673	52.949	0.18613	-0.9683	-0.26722	0.3318	0.48327

Device Test: 53.3 _LsRdson|LowSide/SW3/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 23.0, Upper Limit = 64.0 (MΩ))

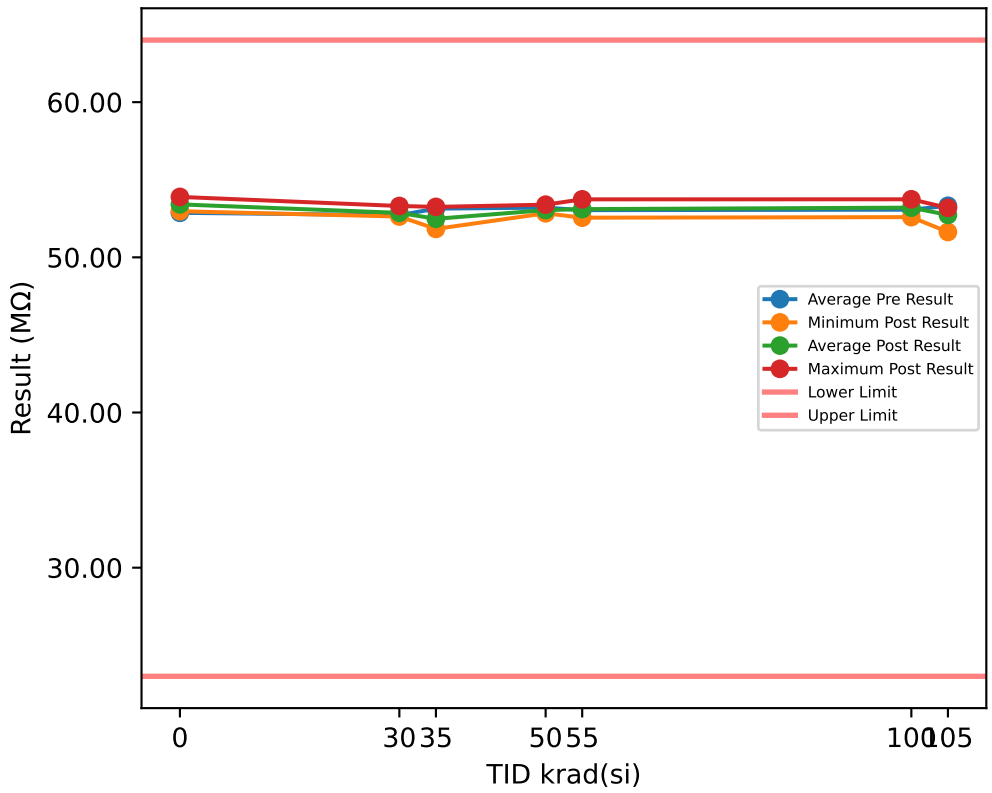
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	52.784	53.853	1.0693
2	0	CU2	52.36	52.798	0.4386
3	0	CU3	52.985	53.463	0.4781
11	30	Unbiased-30krad	52.346	53.128	0.7823
12	30	Unbiased-30krad	52.991	53.396	0.4044
13	30	Unbiased-30krad	52.479	52.314	-0.1648
14	30	Unbiased-30krad	52.925	52.988	0.0634
15	30	Unbiased-30krad	52.993	53.984	0.9913
16	35	Biased-30krad	52.69	53.062	0.372
17	35	Biased-30krad	52.726	52.551	-0.1748
18	35	Biased-30krad	53.309	53.345	0.0359
19	35	Biased-30krad	52.797	52.379	-0.4178
20	35	Biased-30krad	52.224	53.133	0.9082
30	50	Unbiased-50krad	53.166	53.559	0.3932
31	50	Unbiased-50krad	52.446	52.246	-0.1993
32	50	Unbiased-50krad	53.015	53.176	0.1604
33	50	Unbiased-50krad	52.598	52.954	0.3555
34	50	Unbiased-50krad	53.352	53.166	-0.1866
40	55	Biased-50krad	53.102	52.765	-0.3371
41	55	Biased-50krad	52.872	52.397	-0.4753
42	55	Biased-50krad	53.234	52.781	-0.4533
43	55	Biased-50krad	53.359	52.68	-0.6792
44	55	Biased-50krad	52.837	51.769	-1.069
45	100	Unbiased-100krad	52.523	52.246	-0.277
46	100	Unbiased-100krad	53.169	53.209	0.0402
47	100	Unbiased-100krad	52.78	52.479	-0.3013
48	100	Unbiased-100krad	53.027	52.812	-0.2151
49	100	Unbiased-100krad	53.307	53.329	0.0223
50	105	Biased-100krad	53.383	53.296	-0.087
51	105	Biased-100krad	52.42	52.731	0.3108
52	105	Biased-100krad	53.275	53.347	0.072
53	105	Biased-100krad	52.9	52.725	-0.1748
54	105	Biased-100krad	53.141	53.255	0.1141

Test Statistics (MΩ)

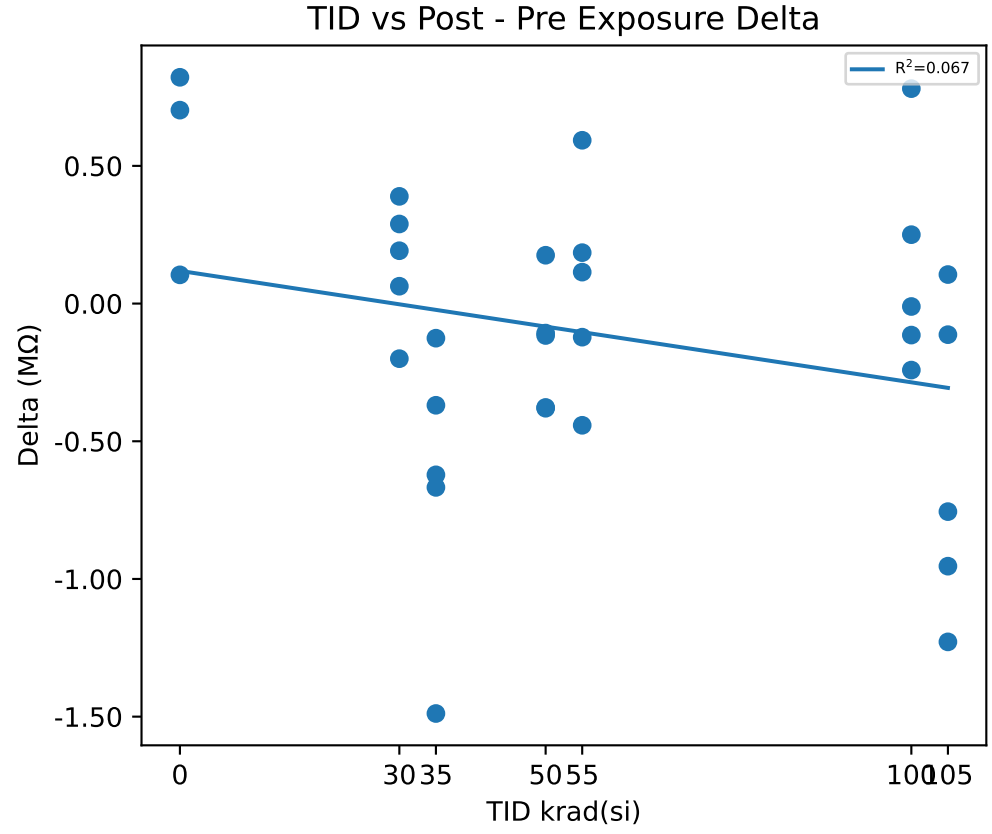
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.36	52.71	52.985	0.31931	52.798	53.372	53.853	0.53344	0.4386	0.662	1.0693	0.35328
30	52.346	52.747	52.993	0.30999	52.314	53.162	53.984	0.6083	-0.1648	0.41532	0.9913	0.48139
35	52.224	52.749	53.309	0.38585	52.379	52.894	53.345	0.40971	-0.4178	0.1447	0.9082	0.51598
50	52.446	52.915	53.352	0.38243	52.246	53.02	53.559	0.48452	-0.1993	0.10464	0.3932	0.2857
55	52.837	53.081	53.359	0.22592	51.769	52.478	52.781	0.42575	-1.069	-0.60278	-0.3371	0.28826
100	52.523	52.961	53.307	0.31301	52.246	52.815	53.329	0.46276	-0.3013	-0.14618	0.0402	0.16511
105	52.42	53.024	53.383	0.38248	52.725	53.071	53.347	0.31459	-0.1748	0.04702	0.3108	0.18833

Device Test: 53.4 _LsRdson|LowSide/SW4/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C

TID vs Result Stats



TID vs Post - Pre Exposure Delta



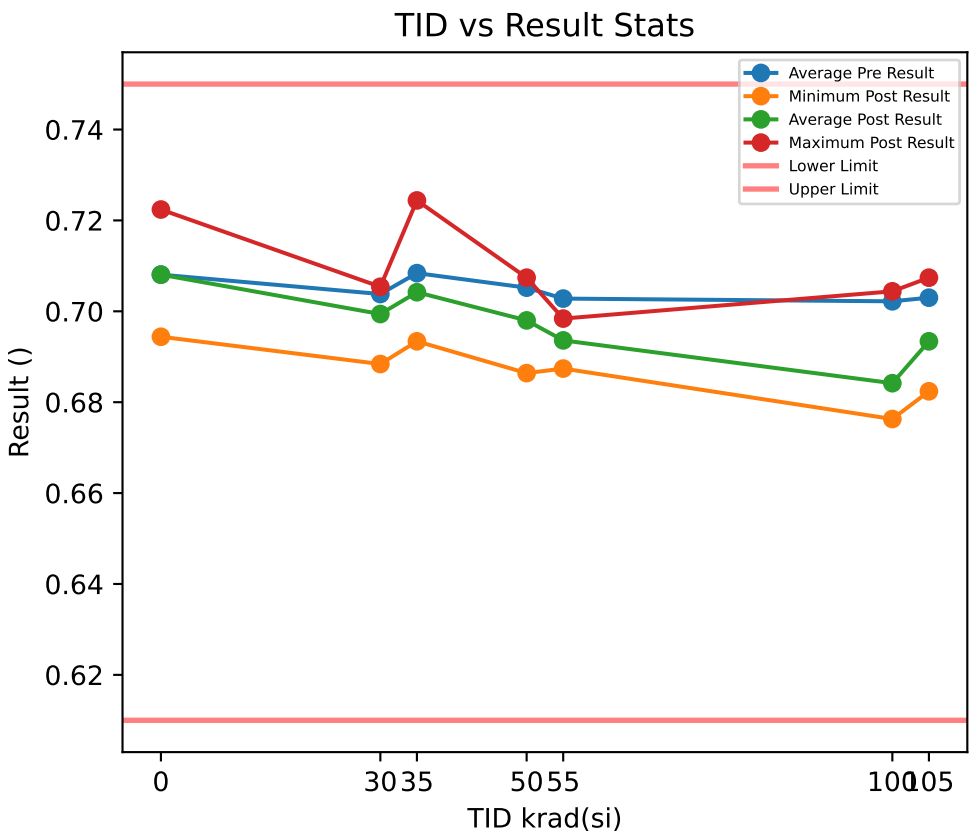
Test Results (Lower Limit = 23.0, Upper Limit = 64.0 (MΩ))

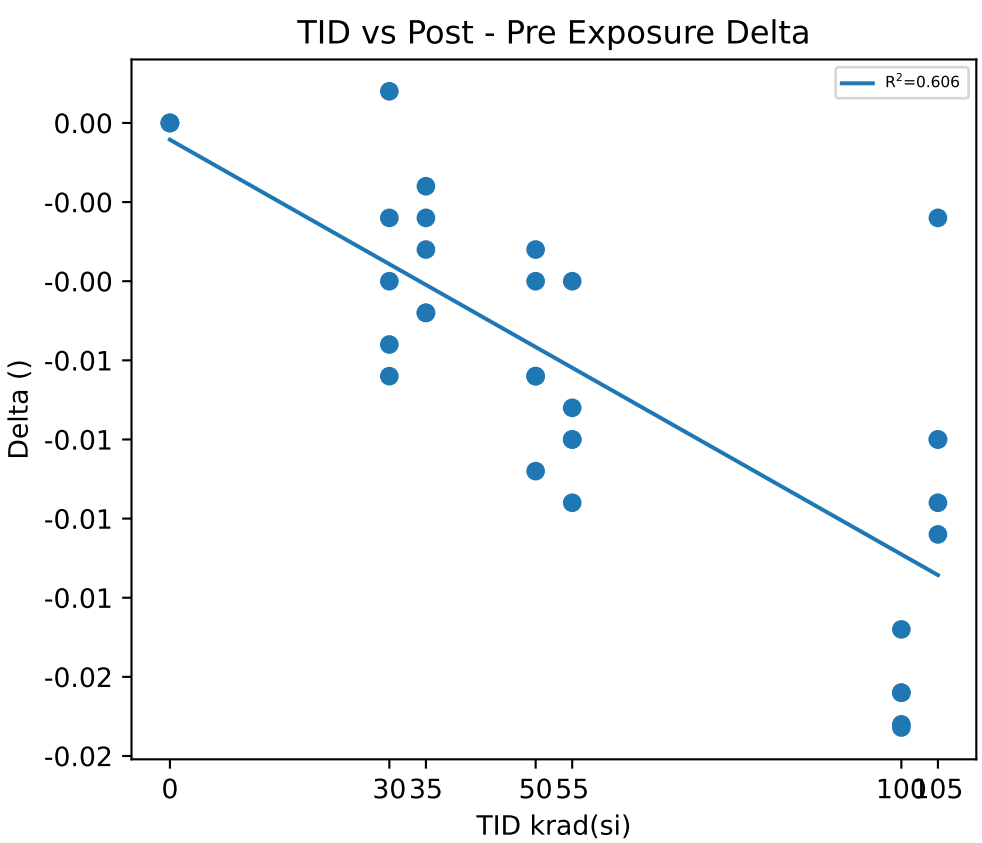
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	52.548	53.37	0.8217
2	0	CU2	53.192	53.894	0.7024
3	0	CU3	52.866	52.971	0.1043
11	30	Unbiased-30krad	52.566	52.629	0.063
12	30	Unbiased-30krad	52.92	53.309	0.3893
13	30	Unbiased-30krad	52.463	52.655	0.1919
14	30	Unbiased-30krad	52.795	53.084	0.289
15	30	Unbiased-30krad	52.85	52.65	-0.2001
16	35	Biased-30krad	53.376	53.251	-0.1257
17	35	Biased-30krad	52.992	52.37	-0.6219
18	35	Biased-30krad	53.089	52.422	-0.6675
19	35	Biased-30krad	52.911	52.542	-0.3693
20	35	Biased-30krad	53.32	51.831	-1.4886
30	50	Unbiased-50krad	53.299	52.922	-0.3772
31	50	Unbiased-50krad	52.883	53.059	0.1755
32	50	Unbiased-50krad	53.501	53.394	-0.1072
33	50	Unbiased-50krad	53.217	52.837	-0.3801
34	50	Unbiased-50krad	53.122	53.006	-0.1159
40	55	Biased-50krad	52.678	52.556	-0.122
41	55	Biased-50krad	53.348	52.906	-0.442
42	55	Biased-50krad	53.144	53.737	0.593
43	55	Biased-50krad	53.133	53.318	0.1849
44	55	Biased-50krad	52.901	53.016	0.1142
45	100	Unbiased-100krad	52.739	53.52	0.7805
46	100	Unbiased-100krad	53.49	53.74	0.2502
47	100	Unbiased-100krad	52.705	52.59	-0.1144
48	100	Unbiased-100krad	53.264	53.023	-0.2415
49	100	Unbiased-100krad	53.149	53.139	-0.0106
50	105	Biased-100krad	53.58	52.824	-0.7555
51	105	Biased-100krad	52.587	51.633	-0.9536
52	105	Biased-100krad	53.058	53.164	0.1054
53	105	Biased-100krad	54.085	52.857	-1.2285
54	105	Biased-100krad	53.298	53.185	-0.1129

Test Statistics (MΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.548	52.869	53.192	0.32171	52.971	53.412	53.894	0.46315	0.1043	0.5428	0.8217	0.38441
30	52.463	52.719	52.92	0.19512	52.629	52.865	53.309	0.31296	-0.2001	0.14662	0.3893	0.22827
35	52.911	53.138	53.376	0.20316	51.831	52.483	53.251	0.50841	-1.4886	-0.6546	-0.1257	0.51428
50	52.883	53.204	53.501	0.22756	52.837	53.044	53.394	0.21299	-0.3801	-0.16098	0.1755	0.23071
55	52.678	53.041	53.348	0.2574	52.556	53.107	53.737	0.44545	-0.442	0.06562	0.593	0.38327
100	52.705	53.07	53.49	0.3403	52.59	53.202	53.74	0.44749	-0.2415	0.13284	0.7805	0.40468
105	52.587	53.322	54.085	0.56109	51.633	52.733	53.185	0.63701	-1.2285	-0.58902	0.1054	0.56535

Device Test: 54.2 _EnSeqThreshold|RISE/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_RISING





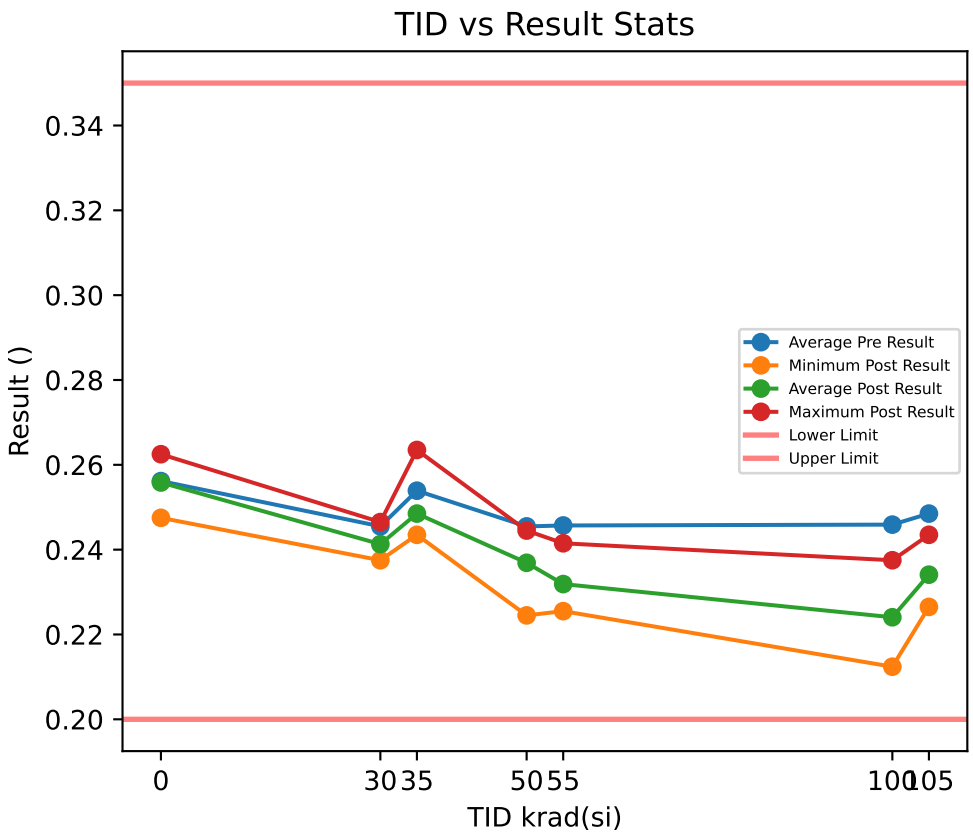
Test Results (Lower Limit = 0.61, Upper Limit = 0.75 ())

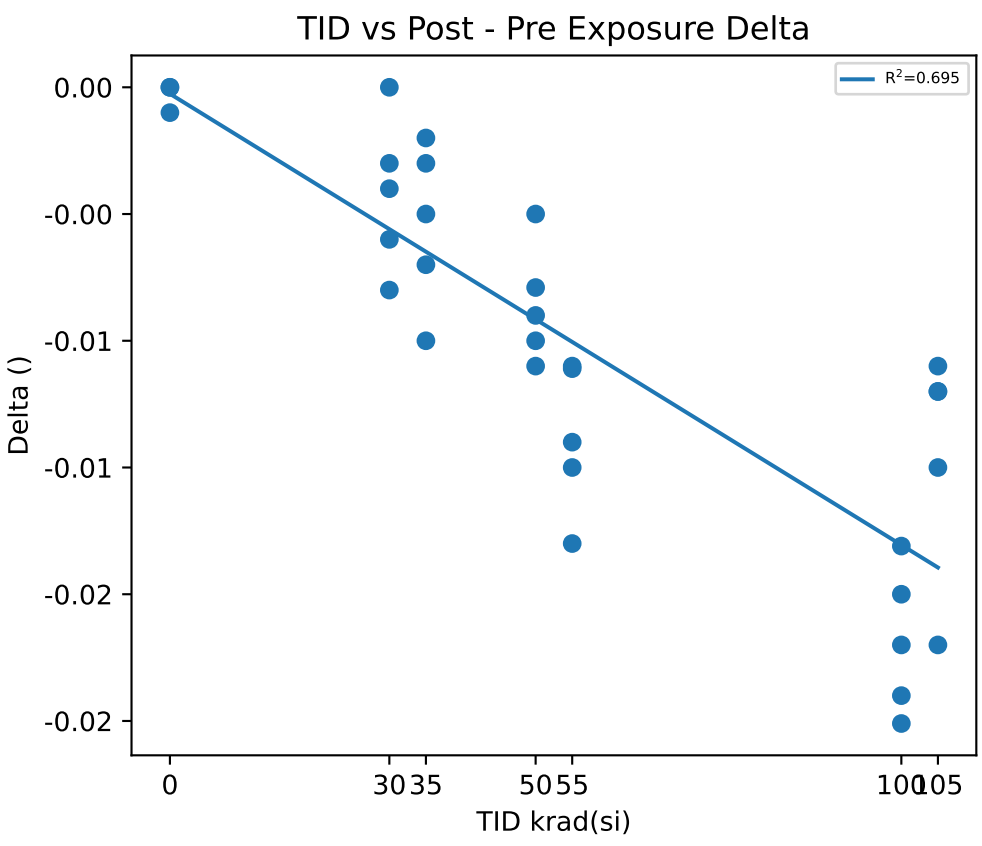
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.6944	0.6944	0
2	0	CU2	0.7224	0.7224	0
3	0	CU3	0.7074	0.7074	0
11	30	Unbiased-30krad	0.7064	0.6994	-0.007
12	30	Unbiased-30krad	0.7074	0.7044	-0.003
13	30	Unbiased-30krad	0.7104	0.7054	-0.005
14	30	Unbiased-30krad	0.6964	0.6884	-0.008
15	30	Unbiased-30krad	0.6984	0.6994	0.001
16	35	Biased-30krad	0.6994	0.6934	-0.006
17	35	Biased-30krad	0.6954	0.6934	-0.002
18	35	Biased-30krad	0.7284	0.7244	-0.004
19	35	Biased-30krad	0.7144	0.7084	-0.006
20	35	Biased-30krad	0.7044	0.7014	-0.003
30	50	Unbiased-50krad	0.7184	0.7074	-0.011
31	50	Unbiased-50krad	0.7084	0.7004	-0.008
32	50	Unbiased-50krad	0.7054	0.6974	-0.008
33	50	Unbiased-50krad	0.6914	0.6864	-0.005
34	50	Unbiased-50krad	0.7024	0.6984	-0.004
40	55	Biased-50krad	0.7074	0.6984	-0.009
41	55	Biased-50krad	0.7034	0.6984	-0.005
42	55	Biased-50krad	0.6994	0.6874	-0.012
43	55	Biased-50krad	0.6974	0.6874	-0.01
44	55	Biased-50krad	0.7064	0.6964	-0.01
45	100	Unbiased-100krad	0.6964	0.6804	-0.016
46	100	Unbiased-100krad	0.7004	0.6814	-0.019
47	100	Unbiased-100krad	0.7224	0.7044	-0.018
48	100	Unbiased-100krad	0.6964	0.6784	-0.018
49	100	Unbiased-100krad	0.6954	0.6763	-0.0191
50	105	Biased-100krad	0.7044	0.6924	-0.012
51	105	Biased-100krad	0.7064	0.6964	-0.01
52	105	Biased-100krad	0.7014	0.6884	-0.013
53	105	Biased-100krad	0.7174	0.7074	-0.01
54	105	Biased-100krad	0.6854	0.6824	-0.003

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6944	0.70807	0.7224	0.014012	0.6944	0.70807	0.7224	0.014012	0	0	0	0
30	0.6964	0.7038	0.7104	0.0060663	0.6884	0.6994	0.7054	0.0067454	-0.008	-0.0044	0.001	0.0035777
35	0.6954	0.7084	0.7284	0.013248	0.6934	0.7042	0.7244	0.012911	-0.006	-0.0042	-0.002	0.0017889
50	0.6914	0.7052	0.7184	0.0097826	0.6864	0.698	0.7074	0.0075697	-0.011	-0.0072	-0.004	0.0027749
55	0.6974	0.7028	0.7074	0.0043359	0.6874	0.6936	0.6984	0.0057184	-0.012	-0.0092	-0.005	0.0025884
100	0.6954	0.7022	0.7224	0.011454	0.6763	0.68418	0.7044	0.011471	-0.0191	-0.01802	-0.016	0.0012458
105	0.6854	0.703	0.7174	0.011546	0.6824	0.6934	0.7074	0.0093808	-0.013	-0.0096	-0.003	0.0039115

Device Test: 54.3 _EnSeqThreshold|FALL/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_FALLING





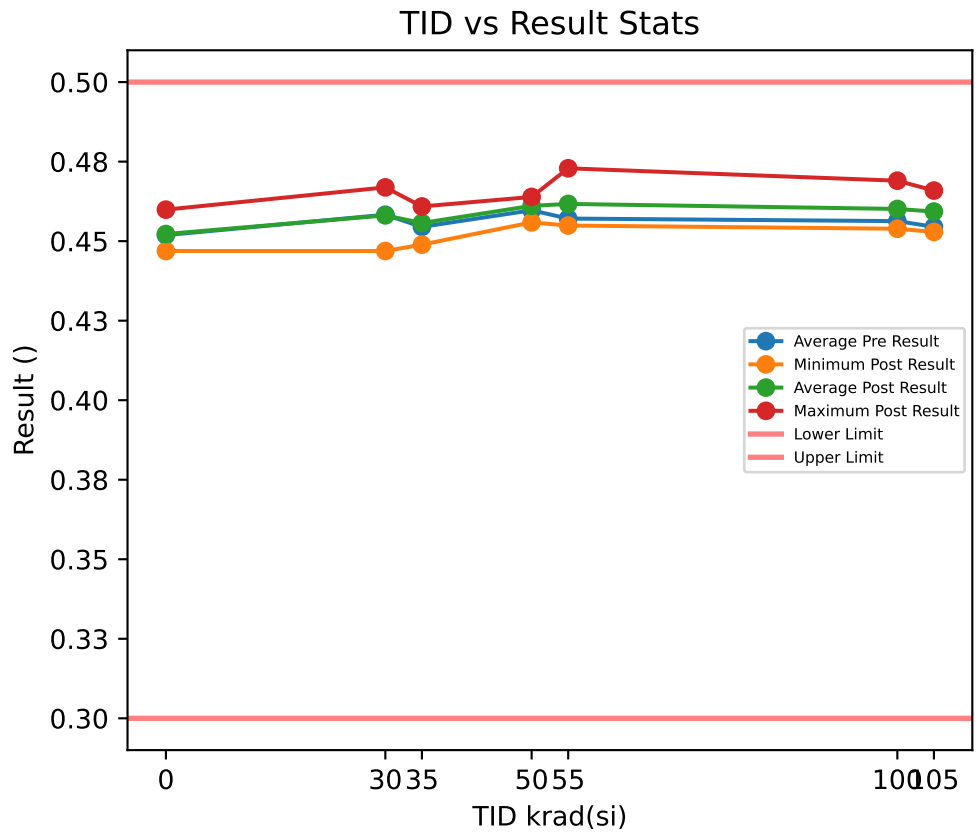
Test Results (Lower Limit = 0.2, Upper Limit = 0.35 ())

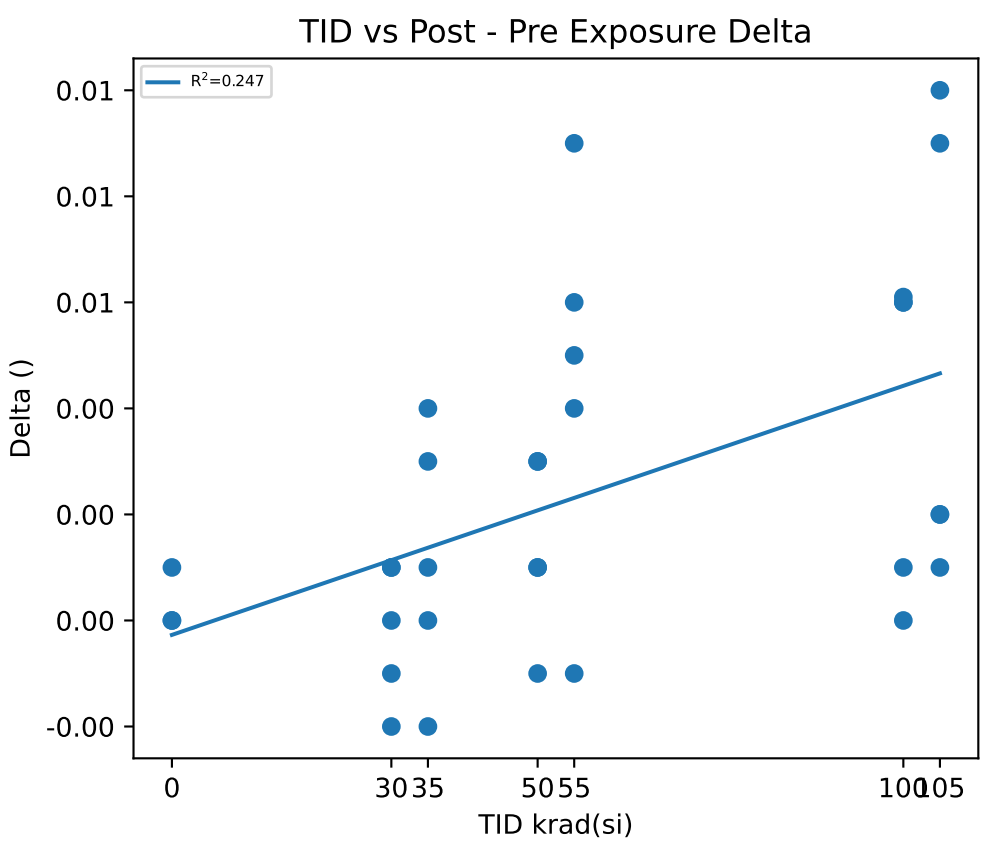
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.2475	0.2475	0
2	0	CU2	0.2635	0.2625	-0.001
3	0	CU3	0.2575	0.2575	0
11	30	Unbiased-30krad	0.2485	0.2405	-0.008
12	30	Unbiased-30krad	0.2405	0.2375	-0.003
13	30	Unbiased-30krad	0.2505	0.2465	-0.004
14	30	Unbiased-30krad	0.2475	0.2415	-0.006
15	30	Unbiased-30krad	0.2405	0.2405	0
16	35	Biased-30krad	0.2535	0.2435	-0.01
17	35	Biased-30krad	0.2495	0.2445	-0.005
18	35	Biased-30krad	0.2655	0.2635	-0.002
19	35	Biased-30krad	0.2545	0.2475	-0.007
20	35	Biased-30krad	0.2465	0.2435	-0.003
30	50	Unbiased-50krad	0.2535	0.2435	-0.01
31	50	Unbiased-50krad	0.2535	0.2445	-0.009
32	50	Unbiased-50krad	0.2465	0.2355	-0.011
33	50	Unbiased-50krad	0.2324	0.2245	-0.0079
34	50	Unbiased-50krad	0.2415	0.2365	-0.005
40	55	Biased-50krad	0.2435	0.2255	-0.018
41	55	Biased-50krad	0.2455	0.2345	-0.011
42	55	Biased-50krad	0.2435	0.2324	-0.0111
43	55	Biased-50krad	0.2405	0.2255	-0.015
44	55	Biased-50krad	0.2555	0.2415	-0.014
45	100	Unbiased-100krad	0.2485	0.2265	-0.022
46	100	Unbiased-100krad	0.2375	0.2124	-0.0251
47	100	Unbiased-100krad	0.2615	0.2375	-0.024
48	100	Unbiased-100krad	0.2415	0.2234	-0.0181
49	100	Unbiased-100krad	0.2405	0.2205	-0.02
50	105	Biased-100krad	0.2485	0.2265	-0.022
51	105	Biased-100krad	0.2495	0.2375	-0.012
52	105	Biased-100krad	0.2485	0.2335	-0.015
53	105	Biased-100krad	0.2545	0.2435	-0.011
54	105	Biased-100krad	0.2415	0.2295	-0.012

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2475	0.25617	0.2635	0.0080829	0.2475	0.25583	0.2625	0.0076376	-0.001	-0.00033333	0	0.00057735
30	0.2405	0.2455	0.2505	0.0046904	0.2375	0.2413	0.2465	0.0032711	-0.008	-0.0042	0	0.0030332
35	0.2465	0.2539	0.2655	0.0072319	0.2435	0.2485	0.2635	0.008544	-0.01	-0.0054	-0.002	0.0032094
50	0.2324	0.24548	0.2535	0.0088967	0.2245	0.2369	0.2445	0.0080187	-0.011	-0.00858	-0.005	0.0023091
55	0.2405	0.2457	0.2555	0.0057619	0.2255	0.23188	0.2415	0.0067284	-0.018	-0.01382	-0.011	0.0029261
100	0.2375	0.2459	0.2615	0.0096073	0.2124	0.22406	0.2375	0.0091604	-0.0251	-0.02184	-0.0181	0.0028588
105	0.2415	0.2485	0.2545	0.0046368	0.2265	0.2341	0.2435	0.0066933	-0.022	-0.0144	-0.011	0.0045056

Device Test: 54.4 _EnSeqThreshold|HYST/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_HYST





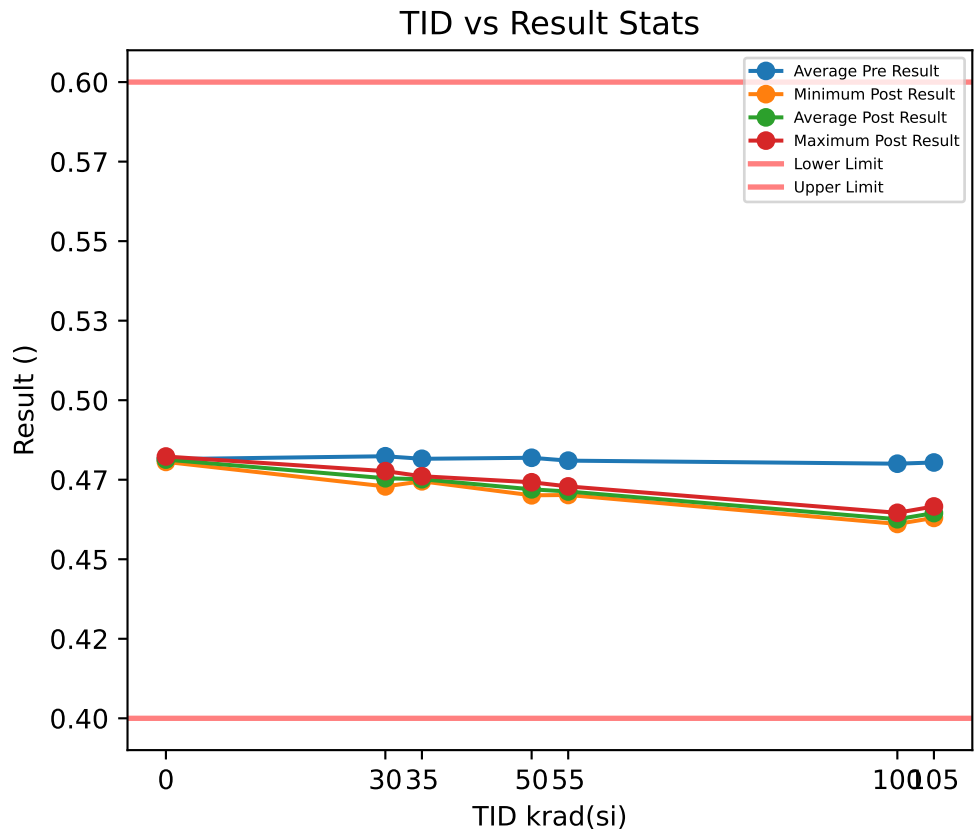
Test Results (Lower Limit = 0.3, Upper Limit = 0.5 ())

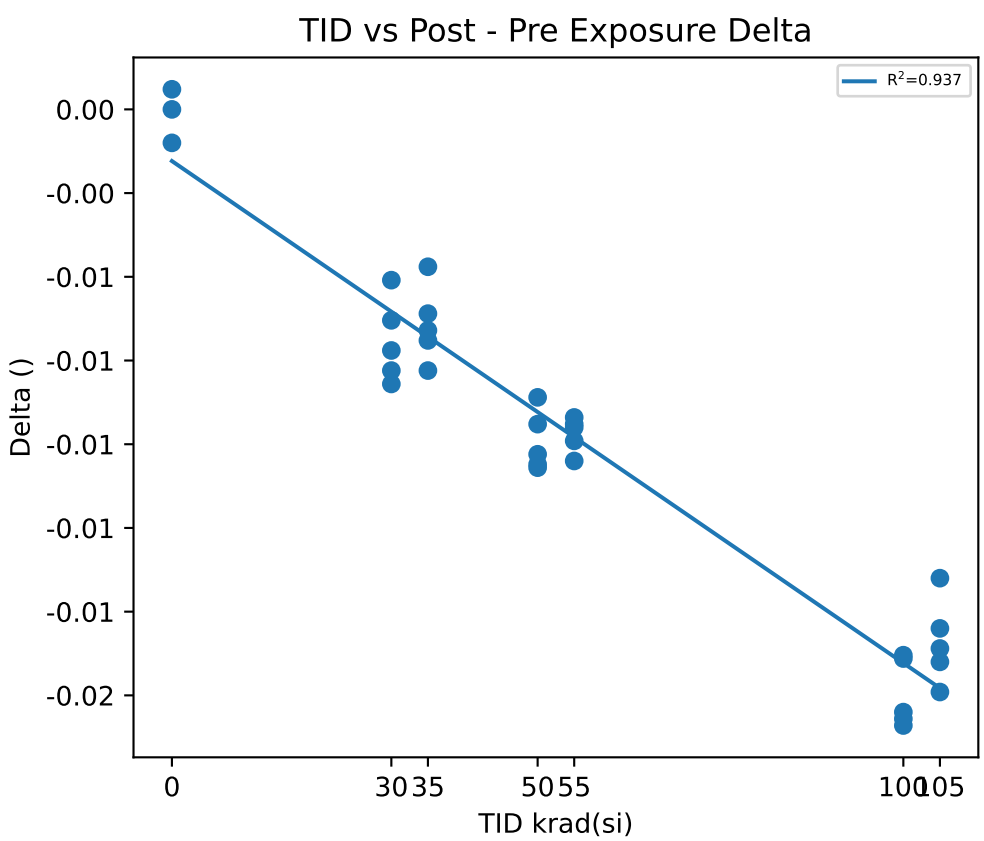
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.4469	0.4469	0
2	0	CU2	0.4589	0.4599	0.001
3	0	CU3	0.4499	0.4499	0
11	30	Unbiased-30krad	0.4579	0.4589	0.001
12	30	Unbiased-30krad	0.4669	0.4669	0
13	30	Unbiased-30krad	0.4599	0.4589	-0.001
14	30	Unbiased-30krad	0.4489	0.4469	-0.002
15	30	Unbiased-30krad	0.4579	0.4589	0.001
16	35	Biased-30krad	0.4459	0.4499	0.004
17	35	Biased-30krad	0.4459	0.4489	0.003
18	35	Biased-30krad	0.4629	0.4609	-0.002
19	35	Biased-30krad	0.4599	0.4609	0.001
20	35	Biased-30krad	0.4579	0.4579	0
30	50	Unbiased-50krad	0.4649	0.4639	-0.001
31	50	Unbiased-50krad	0.4549	0.4559	0.001
32	50	Unbiased-50krad	0.4589	0.4619	0.003
33	50	Unbiased-50krad	0.4589	0.4619	0.003
34	50	Unbiased-50krad	0.4609	0.4619	0.001
40	55	Biased-50krad	0.4639	0.4729	0.009
41	55	Biased-50krad	0.4579	0.4639	0.006
42	55	Biased-50krad	0.4559	0.4549	-0.001
43	55	Biased-50krad	0.4569	0.4619	0.005
44	55	Biased-50krad	0.4509	0.4549	0.004
45	100	Unbiased-100krad	0.4479	0.4539	0.006
46	100	Unbiased-100krad	0.4629	0.469	0.0061
47	100	Unbiased-100krad	0.4609	0.4669	0.006
48	100	Unbiased-100krad	0.4549	0.4549	0
49	100	Unbiased-100krad	0.4549	0.4559	0.001
50	105	Biased-100krad	0.4559	0.4659	0.01
51	105	Biased-100krad	0.4569	0.4589	0.002
52	105	Biased-100krad	0.4529	0.4549	0.002
53	105	Biased-100krad	0.4629	0.4639	0.001
54	105	Biased-100krad	0.4439	0.4529	0.009

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4469	0.4519	0.4589	0.006245	0.4469	0.45223	0.4599	0.0068069	0	0.00033333	0.001	0.00057735
30	0.4489	0.4583	0.4669	0.0064265	0.4469	0.4581	0.4669	0.0071554	-0.002	-0.0002	0.001	0.0013038
35	0.4459	0.4545	0.4629	0.0080498	0.4489	0.4557	0.4609	0.0058907	-0.002	0.0012	0.004	0.0023875
50	0.4549	0.4597	0.4649	0.0036332	0.4559	0.4611	0.4639	0.0030332	-0.001	0.0014	0.003	0.0016733
55	0.4509	0.4571	0.4639	0.0046583	0.4549	0.4617	0.4729	0.0074632	-0.001	0.0046	0.009	0.0036469
100	0.4479	0.4563	0.4629	0.0058992	0.4539	0.46012	0.469	0.0072209	0	0.00382	0.0061	0.0030516
105	0.4439	0.4545	0.4629	0.0069498	0.4529	0.4593	0.4659	0.0055946	0.001	0.0048	0.01	0.0043243

Device Test: 54.5 _EnSeqThreshold|OPEN/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_OPEN





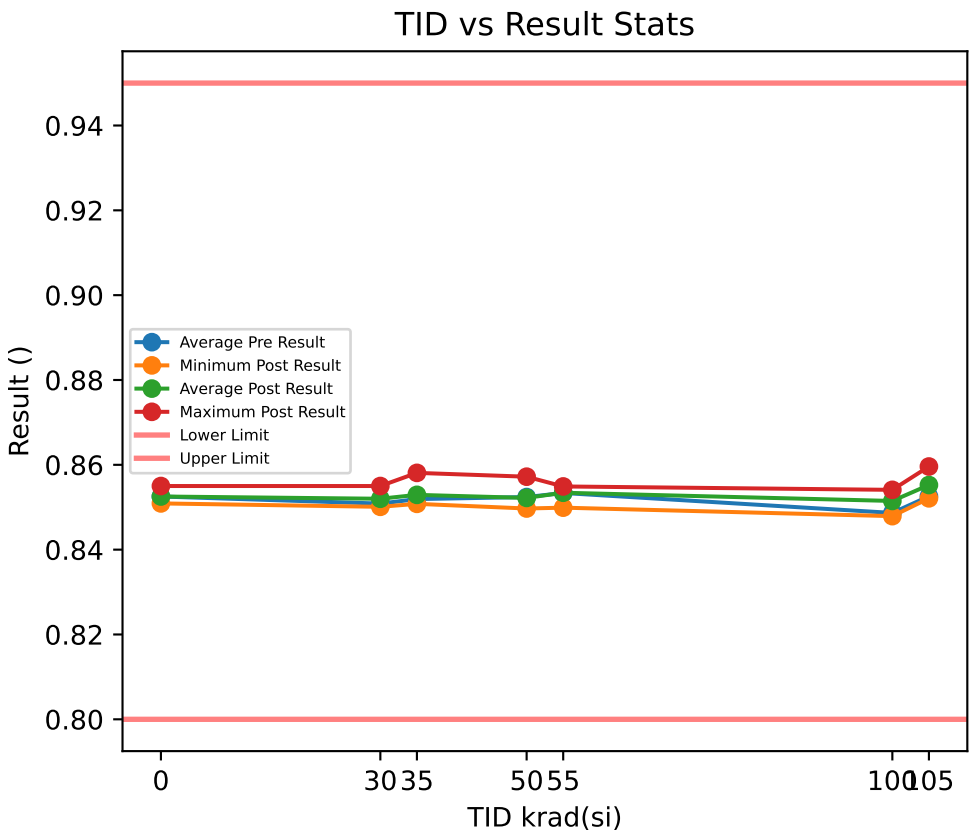
Test Results (Lower Limit = 0.4, Upper Limit = 0.6 ())

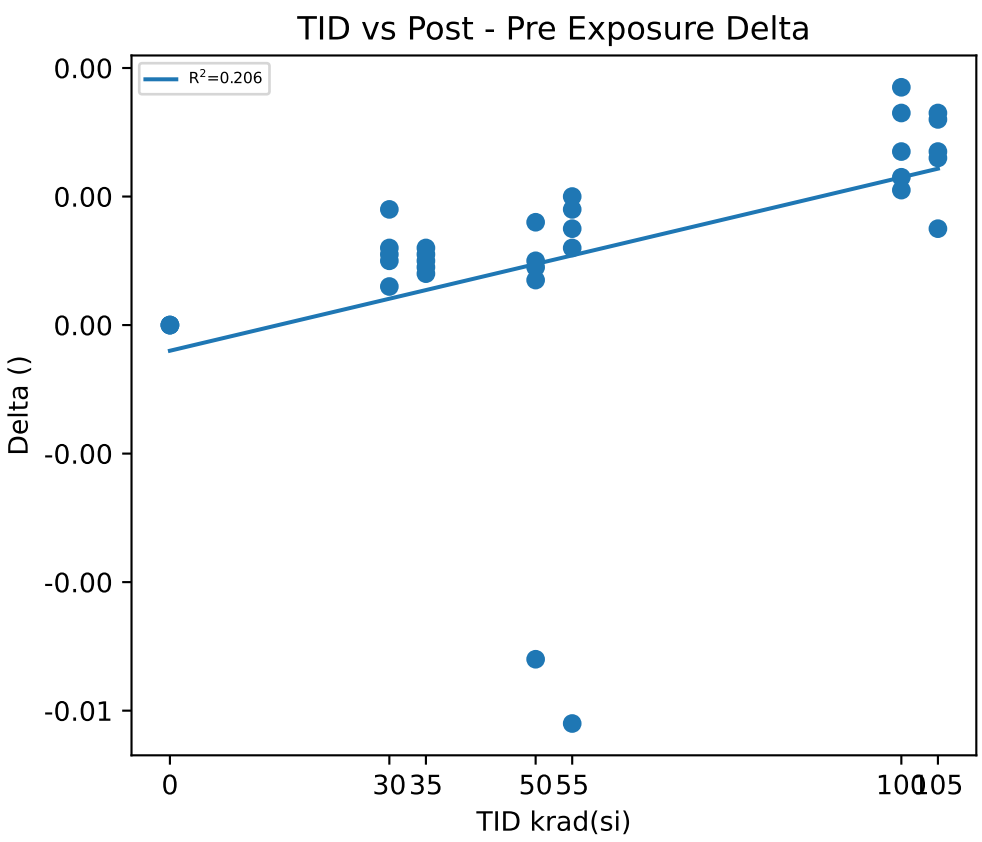
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.4823	0.4823	0
2	0	CU2	0.4805	0.4811	0.0006
3	0	CU3	0.4816	0.4806	-0.001
11	30	Unbiased-30krad	0.4802	0.4751	-0.0051
12	30	Unbiased-30krad	0.4823	0.476	-0.0063
13	30	Unbiased-30krad	0.4811	0.4729	-0.0082
14	30	Unbiased-30krad	0.4828	0.4756	-0.0072
15	30	Unbiased-30krad	0.4855	0.4777	-0.0078
16	35	Biased-30krad	0.4804	0.4757	-0.0047
17	35	Biased-30krad	0.4827	0.4761	-0.0066
18	35	Biased-30krad	0.4827	0.4749	-0.0078
19	35	Biased-30krad	0.4815	0.4746	-0.0069
20	35	Biased-30krad	0.4806	0.4745	-0.0061
30	50	Unbiased-50krad	0.4798	0.4712	-0.0086
31	50	Unbiased-50krad	0.4795	0.4701	-0.0094
32	50	Unbiased-50krad	0.4827	0.472	-0.0107
33	50	Unbiased-50krad	0.483	0.4724	-0.0106
34	50	Unbiased-50krad	0.4845	0.4742	-0.0103
40	55	Biased-50krad	0.4801	0.4709	-0.0092
41	55	Biased-50krad	0.4818	0.4713	-0.0105
42	55	Biased-50krad	0.4828	0.4729	-0.0099
43	55	Biased-50krad	0.4806	0.4712	-0.0094
44	55	Biased-50krad	0.4797	0.4702	-0.0095
45	100	Unbiased-100krad	0.4787	0.4624	-0.0163
46	100	Unbiased-100krad	0.481	0.4646	-0.0164
47	100	Unbiased-100krad	0.4796	0.4616	-0.018
48	100	Unbiased-100krad	0.4795	0.4611	-0.0184
49	100	Unbiased-100krad	0.4814	0.4632	-0.0182
50	105	Biased-100krad	0.4806	0.4666	-0.014
51	105	Biased-100krad	0.4798	0.4633	-0.0165
52	105	Biased-100krad	0.4823	0.4649	-0.0174
53	105	Biased-100krad	0.4791	0.463	-0.0161
54	105	Biased-100krad	0.4803	0.4648	-0.0155

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4805	0.48147	0.4823	0.00090738	0.4806	0.48133	0.4823	0.00087369	-0.001	-0.00013333	0.0006	0.00080829
30	0.4802	0.48238	0.4855	0.0020192	0.4729	0.47546	0.4777	0.0017329	-0.0082	-0.00692	-0.0051	0.0012438
35	0.4804	0.48158	0.4827	0.0011032	0.4745	0.47516	0.4761	0.00070569	-0.0078	-0.00642	-0.0047	0.0011432
50	0.4795	0.4819	0.4845	0.0021668	0.4701	0.47198	0.4742	0.0015205	-0.0107	-0.00992	-0.0086	0.00089833
55	0.4797	0.481	0.4828	0.0012787	0.4702	0.4713	0.4729	0.00099247	-0.0105	-0.0097	-0.0092	0.00051478
100	0.4787	0.48004	0.4814	0.0011238	0.4611	0.46258	0.4646	0.0013828	-0.0184	-0.01746	-0.0163	0.0010237
105	0.4791	0.48042	0.4823	0.0011946	0.463	0.46452	0.4666	0.0014446	-0.0174	-0.0159	-0.014	0.0012669

Device Test: 55.1 _EnSeq|PowerUp/VS1_to_COMP2/3/3///90.9/634//1.8//12/@V_CHANNEL_ON





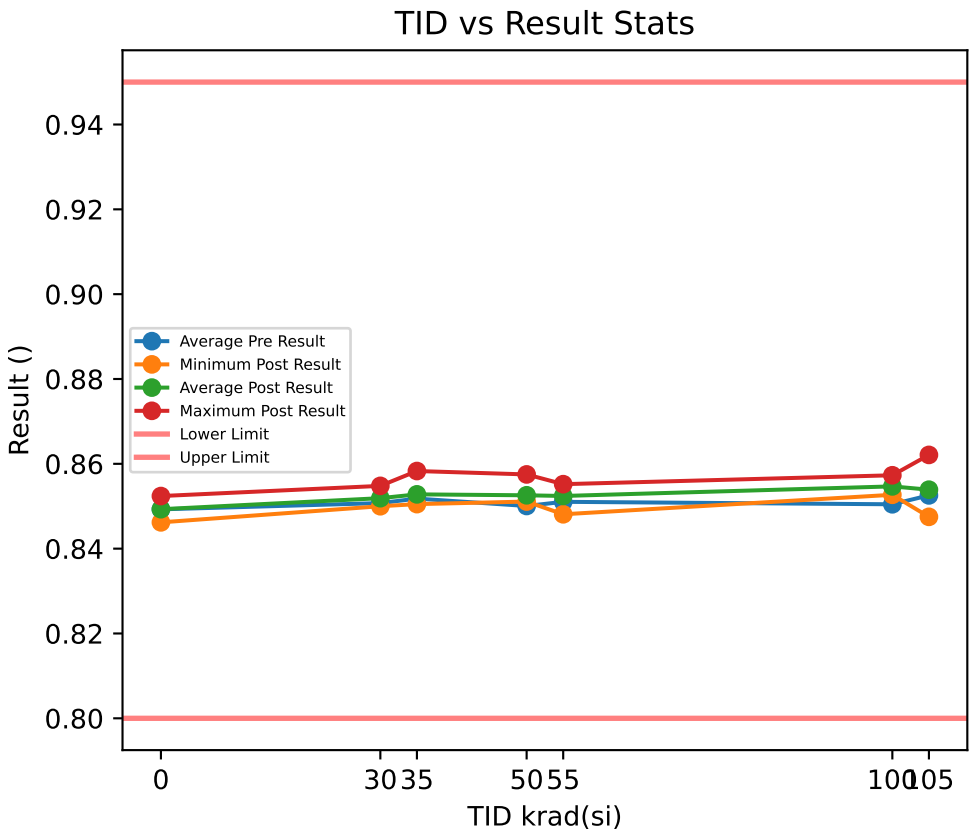
Test Results (Lower Limit = 0.8, Upper Limit = 0.95 ())

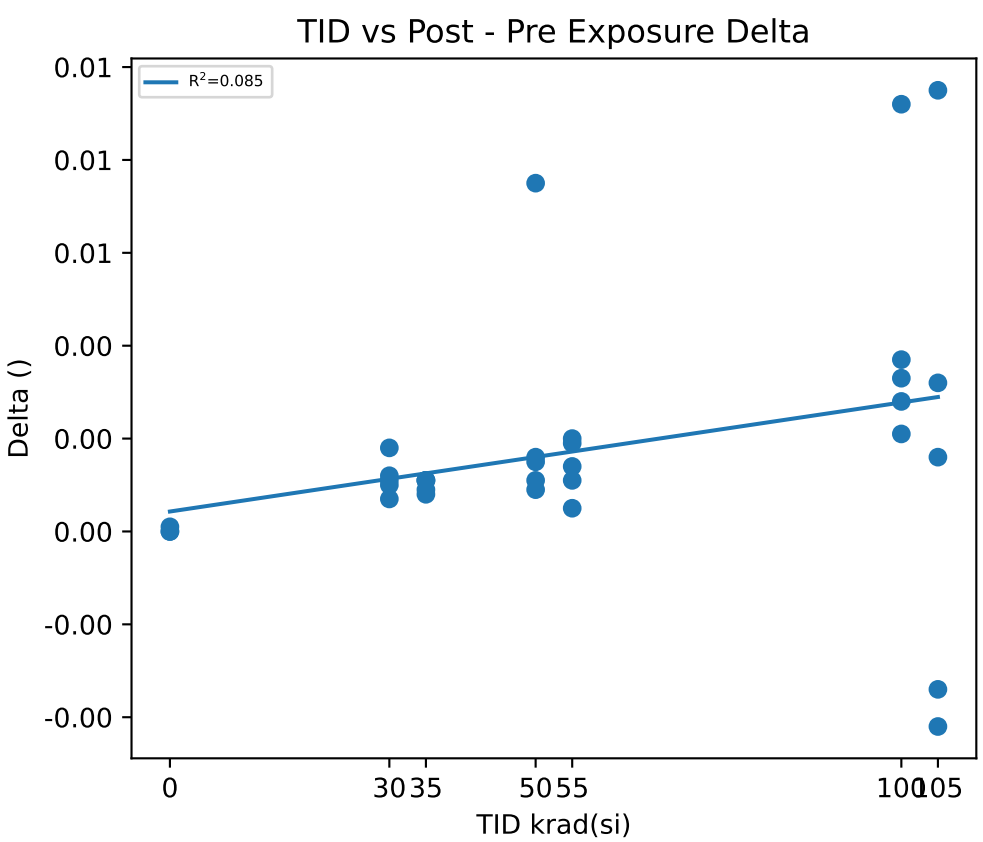
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.8509	0.8509	0
2	0	CU2	0.855	0.855	0
3	0	CU3	0.8517	0.8517	0
11	30	Unbiased-30krad	0.8535	0.8547	0.0012
12	30	Unbiased-30krad	0.8491	0.8501	0.001
13	30	Unbiased-30krad	0.849	0.8501	0.0011
14	30	Unbiased-30krad	0.8532	0.855	0.0018
15	30	Unbiased-30krad	0.8495	0.8501	0.0006
16	35	Biased-30krad	0.8573	0.8581	0.0008
17	35	Biased-30krad	0.8503	0.8512	0.0009
18	35	Biased-30krad	0.8516	0.8527	0.0011
19	35	Biased-30krad	0.8496	0.8508	0.0012
20	35	Biased-30krad	0.8508	0.8518	0.001
30	50	Unbiased-50krad	0.849	0.8497	0.0007
31	50	Unbiased-50krad	0.8564	0.8512	-0.0052
32	50	Unbiased-50krad	0.8556	0.8572	0.0016
33	50	Unbiased-50krad	0.8499	0.8509	0.001
34	50	Unbiased-50krad	0.8511	0.852	0.0009
40	55	Biased-50krad	0.8523	0.8543	0.002
41	55	Biased-50krad	0.8518	0.8536	0.0018
42	55	Biased-50krad	0.8534	0.8549	0.0015
43	55	Biased-50krad	0.8532	0.8544	0.0012
44	55	Biased-50krad	0.8561	0.8499	-0.0062
45	100	Unbiased-100krad	0.8446	0.8479	0.0033
46	100	Unbiased-100krad	0.8501	0.8522	0.0021
47	100	Unbiased-100krad	0.8504	0.8541	0.0037
48	100	Unbiased-100krad	0.8475	0.8498	0.0023
49	100	Unbiased-100krad	0.8507	0.8534	0.0027
50	105	Biased-100krad	0.8506	0.8521	0.0015
51	105	Biased-100krad	0.8563	0.8596	0.0033
52	105	Biased-100krad	0.8508	0.8535	0.0027
53	105	Biased-100krad	0.8543	0.8575	0.0032
54	105	Biased-100krad	0.8509	0.8535	0.0026

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.8509	0.85253	0.855	0.0021733	0.8509	0.85253	0.855	0.0021733	0	0	0	0
30	0.849	0.85086	0.8535	0.0022832	0.8501	0.852	0.855	0.0026038	0.0006	0.00114	0.0018	0.00043359
35	0.8496	0.85192	0.8573	0.0030947	0.8508	0.85292	0.8581	0.0029828	0.0008	0.001	0.0012	0.00015811
50	0.849	0.8524	0.8564	0.0033816	0.8497	0.8522	0.8572	0.0029146	-0.0052	-0.0002	0.0016	0.0028151
55	0.8518	0.85336	0.8561	0.0016652	0.8499	0.85342	0.8549	0.0020216	-0.0062	6e-05	0.002	0.0035125
100	0.8446	0.84866	0.8507	0.0026025	0.8479	0.85148	0.8541	0.002584	0.0021	0.00282	0.0037	0.00067231
105	0.8506	0.85258	0.8563	0.002584	0.8521	0.85524	0.8596	0.0031635	0.0015	0.00266	0.0033	0.00071624

Device Test: 55.2 _EnSeq|PowerUp/VS2_to_COMP3/3/3///90.9/634//1.8//12/@V_CHANNEL_ON





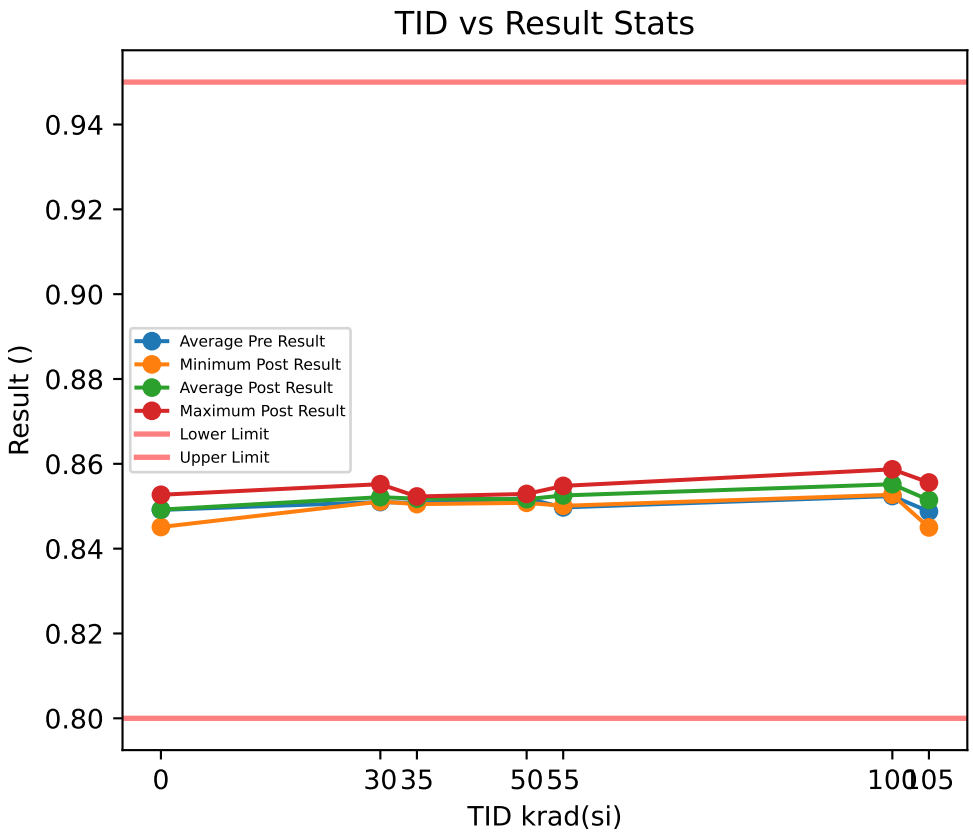
Test Results (Lower Limit = 0.8, Upper Limit = 0.95 ())

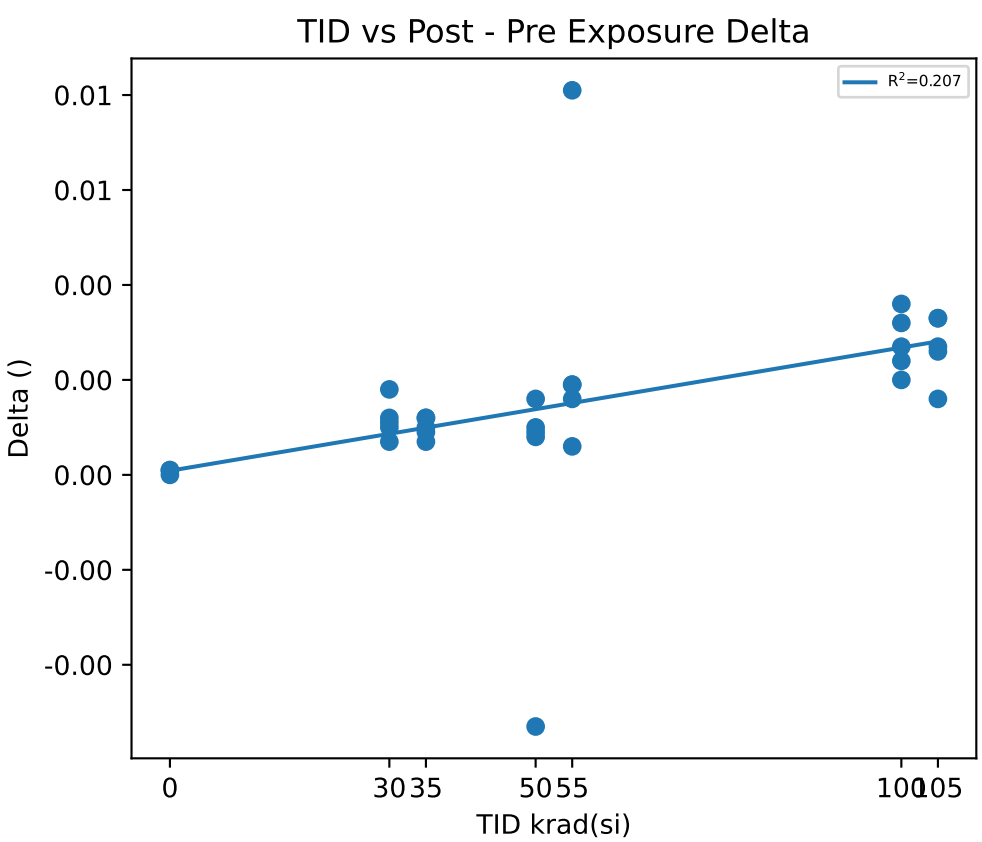
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.8462	0.8462	0
2	0	CU2	0.8523	0.8524	0.0001
3	0	CU3	0.8493	0.8493	0
11	30	Unbiased-30krad	0.8536	0.8548	0.0012
12	30	Unbiased-30krad	0.849	0.85	0.001
13	30	Unbiased-30krad	0.8509	0.852	0.0011
14	30	Unbiased-30krad	0.8504	0.8522	0.0018
15	30	Unbiased-30krad	0.8498	0.8505	0.0007
16	35	Biased-30krad	0.8512	0.852	0.0008
17	35	Biased-30krad	0.8574	0.8583	0.0009
18	35	Biased-30krad	0.8494	0.8505	0.0011
19	35	Biased-30krad	0.8508	0.8519	0.0011
20	35	Biased-30krad	0.8502	0.8513	0.0011
30	50	Unbiased-50krad	0.85	0.8575	0.0075
31	50	Unbiased-50krad	0.85	0.8515	0.0015
32	50	Unbiased-50krad	0.8495	0.8511	0.0016
33	50	Unbiased-50krad	0.85	0.8511	0.0011
34	50	Unbiased-50krad	0.8508	0.8517	0.0009
40	55	Biased-50krad	0.8532	0.8552	0.002
41	55	Biased-50krad	0.8505	0.8524	0.0019
42	55	Biased-50krad	0.8467	0.8481	0.0014
43	55	Biased-50krad	0.8531	0.8542	0.0011
44	55	Biased-50krad	0.8517	0.8522	0.0005
45	100	Unbiased-100krad	0.8511	0.8544	0.0033
46	100	Unbiased-100krad	0.8506	0.8527	0.0021
47	100	Unbiased-100krad	0.851	0.8547	0.0037
48	100	Unbiased-100krad	0.8481	0.8573	0.0092
49	100	Unbiased-100krad	0.8515	0.8543	0.0028
50	105	Biased-100krad	0.852	0.8536	0.0016
51	105	Biased-100krad	0.8509	0.8475	-0.0034
52	105	Biased-100krad	0.853	0.8488	-0.0042
53	105	Biased-100krad	0.8543	0.8575	0.0032
54	105	Biased-100krad	0.8526	0.8621	0.0095

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.8462	0.84927	0.8523	0.0030501	0.8462	0.8493	0.8524	0.0031	0	3.3333e-05	0.0001	5.7735e-05
30	0.849	0.85074	0.8536	0.0017487	0.85	0.8519	0.8548	0.0018762	0.0007	0.00116	0.0018	0.00040373
35	0.8494	0.8518	0.8574	0.0032031	0.8505	0.8528	0.8583	0.0031321	0.0008	0.001	0.0011	0.00014142
50	0.8495	0.85006	0.8508	0.0004669	0.8511	0.85258	0.8575	0.0027626	0.0009	0.00252	0.0075	0.0027986
55	0.8467	0.85104	0.8532	0.002668	0.8481	0.85242	0.8552	0.0027207	0.0005	0.00138	0.002	0.000614
100	0.8481	0.85046	0.8515	0.0013576	0.8527	0.85468	0.8573	0.0016589	0.0021	0.00422	0.0092	0.0028473
105	0.8509	0.85256	0.8543	0.0012542	0.8475	0.8539	0.8621	0.0060675	-0.0042	0.00134	0.0095	0.0055514

Device Test: 55.3 _EnSeq|PowerUp/VS3_to_COMP4/3/3///90.9/634//1.8//12/@V_CHANNEL_ON





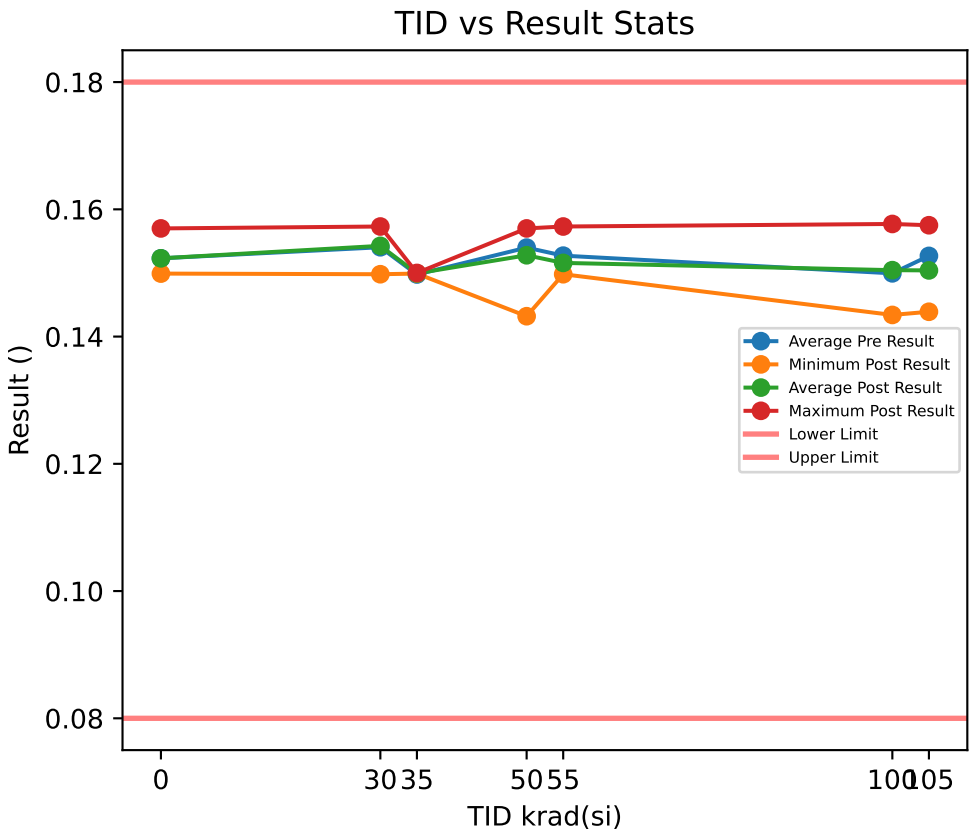
Test Results (Lower Limit = 0.8, Upper Limit = 0.95 ())

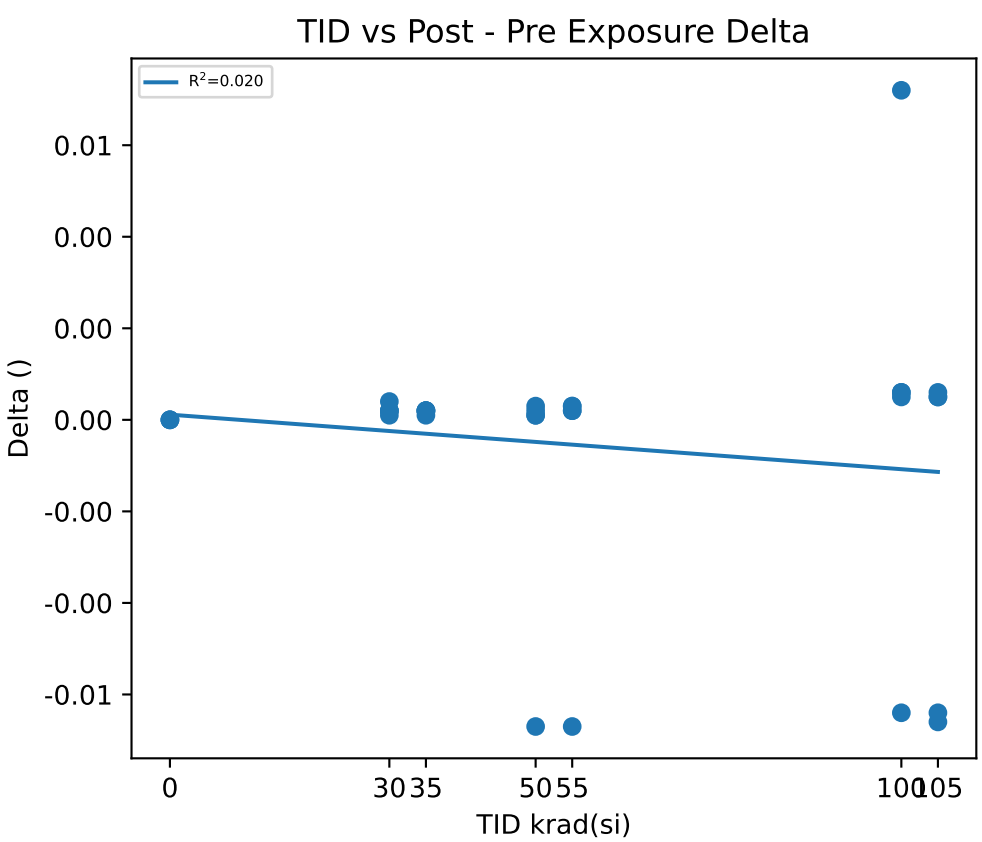
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.845	0.8451	0.0001
2	0	CU2	0.8526	0.8527	0.0001
3	0	CU3	0.8498	0.8498	0
11	30	Unbiased-30krad	0.854	0.8552	0.0012
12	30	Unbiased-30krad	0.851	0.852	0.001
13	30	Unbiased-30krad	0.85	0.8511	0.0011
14	30	Unbiased-30krad	0.8493	0.8511	0.0018
15	30	Unbiased-30krad	0.8506	0.8513	0.0007
16	35	Biased-30krad	0.8512	0.8519	0.0007
17	35	Biased-30krad	0.8514	0.8523	0.0009
18	35	Biased-30krad	0.8508	0.852	0.0012
19	35	Biased-30krad	0.851	0.8522	0.0012
20	35	Biased-30krad	0.8495	0.8505	0.001
30	50	Unbiased-50krad	0.85	0.8508	0.0008
31	50	Unbiased-50krad	0.8582	0.8529	-0.0053
32	50	Unbiased-50krad	0.8495	0.8511	0.0016
33	50	Unbiased-50krad	0.8503	0.8513	0.001
34	50	Unbiased-50krad	0.8513	0.8522	0.0009
40	55	Biased-50krad	0.8529	0.8548	0.0019
41	55	Biased-50krad	0.8496	0.8515	0.0019
42	55	Biased-50krad	0.8524	0.854	0.0016
43	55	Biased-50krad	0.8442	0.8523	0.0081
44	55	Biased-50krad	0.8495	0.8501	0.0006
45	100	Unbiased-100krad	0.8504	0.8536	0.0032
46	100	Unbiased-100krad	0.8507	0.8527	0.002
47	100	Unbiased-100krad	0.8506	0.8542	0.0036
48	100	Unbiased-100krad	0.8543	0.8567	0.0024
49	100	Unbiased-100krad	0.856	0.8587	0.0027
50	105	Biased-100krad	0.8434	0.845	0.0016
51	105	Biased-100krad	0.8511	0.8544	0.0033
52	105	Biased-100krad	0.8529	0.8556	0.0027
53	105	Biased-100krad	0.8456	0.8489	0.0033
54	105	Biased-100krad	0.8508	0.8534	0.0026

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.845	0.84913	0.8526	0.0038436	0.8451	0.8492	0.8527	0.0038354	0	6.6667e-05	0.0001	5.7735e-05
30	0.8493	0.85098	0.854	0.0018061	0.8511	0.85214	0.8552	0.0017501	0.0007	0.00116	0.0018	0.00040373
35	0.8495	0.85078	0.8514	0.00074967	0.8505	0.85178	0.8523	0.0007328	0.0007	0.001	0.0012	0.00021213
50	0.8495	0.85186	0.8582	0.0036046	0.8508	0.85166	0.8529	0.00086776	-0.0053	-0.0002	0.0016	0.0028679
55	0.8442	0.84972	0.8529	0.0034579	0.8501	0.85254	0.8548	0.0018929	0.0006	0.00282	0.0081	0.0029995
100	0.8504	0.8524	0.856	0.0025836	0.8527	0.85518	0.8587	0.0024652	0.002	0.00278	0.0036	0.00063403
105	0.8434	0.84876	0.8529	0.0040464	0.845	0.85146	0.8556	0.0044111	0.0016	0.0027	0.0033	0.00069642

Device Test: 55.4 _EnSeq|PowerDown/VS4_to_COMP3/3/3///90.9/634//1.8//12/@V_CHANNEL_OFF





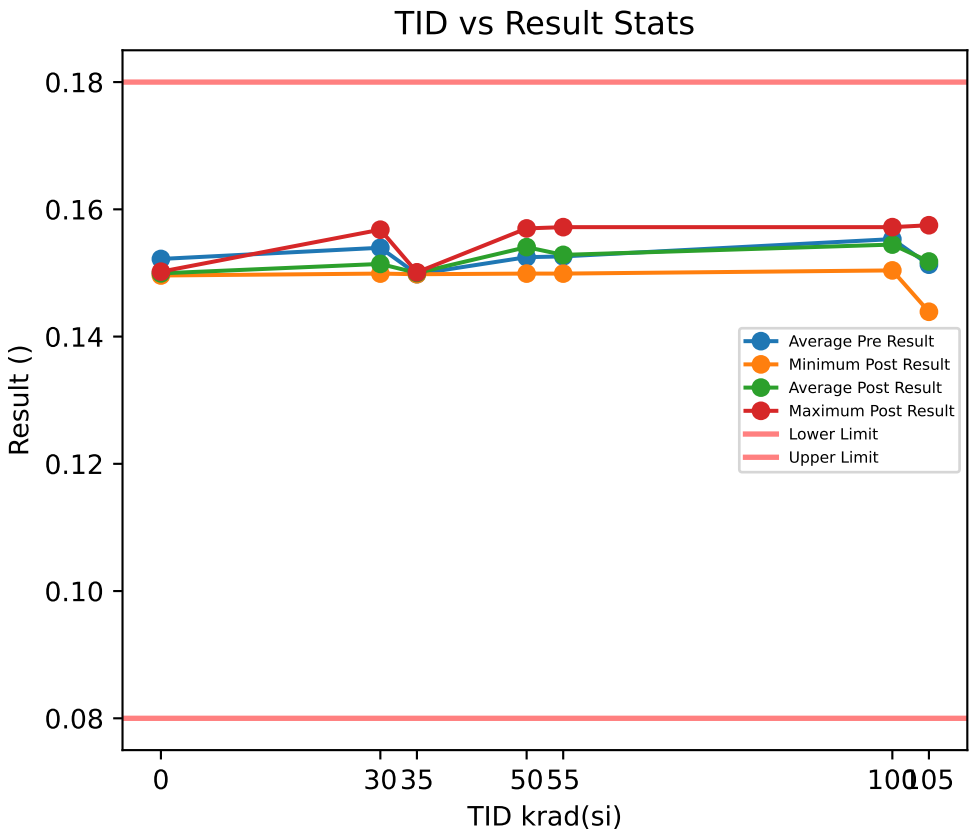
Test Results (Lower Limit = 0.08, Upper Limit = 0.18 ())

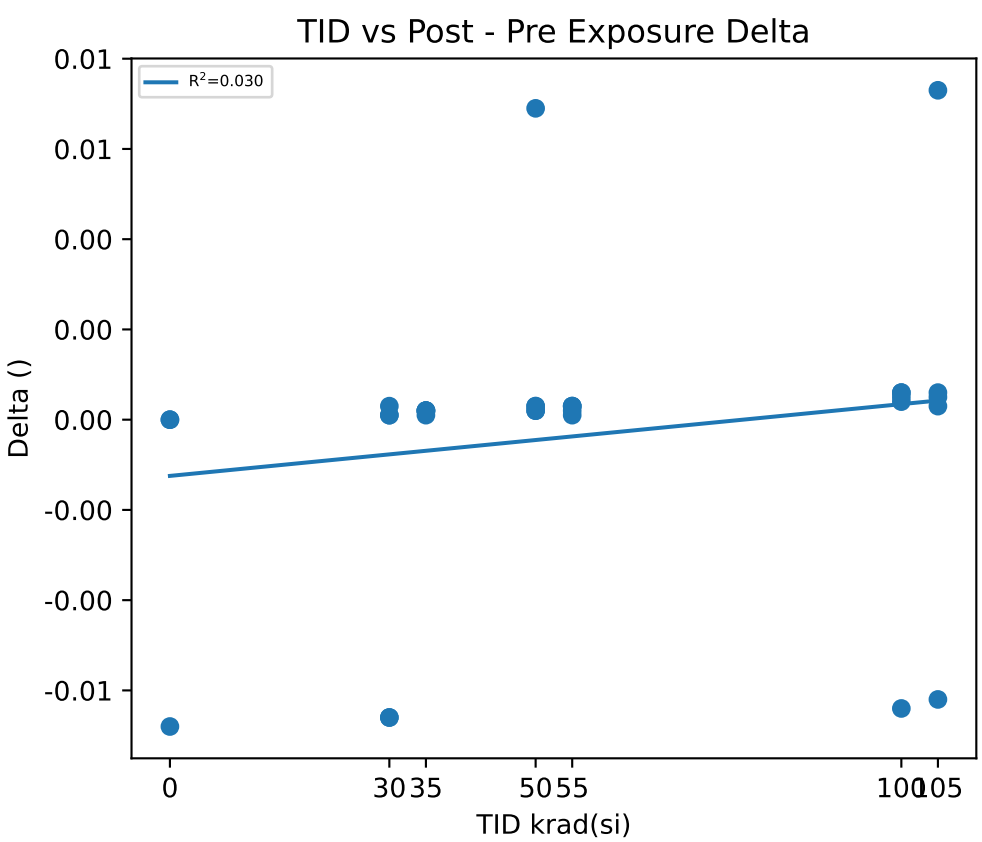
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.15	0.15	0
2	0	CU2	0.157	0.157	0
3	0	CU3	0.1499	0.1499	0
11	30	Unbiased-30krad	0.1506	0.1508	0.0002
12	30	Unbiased-30krad	0.1563	0.1565	0.0002
13	30	Unbiased-30krad	0.1496	0.1498	0.0002
14	30	Unbiased-30krad	0.1569	0.1573	0.0004
15	30	Unbiased-30krad	0.1568	0.1569	0.0001
16	35	Biased-30krad	0.1499	0.15	0.0001
17	35	Biased-30krad	0.1497	0.1499	0.0002
18	35	Biased-30krad	0.1497	0.1499	0.0002
19	35	Biased-30krad	0.1498	0.15	0.0002
20	35	Biased-30krad	0.1497	0.1499	0.0002
30	50	Unbiased-50krad	0.1499	0.15	0.0001
31	50	Unbiased-50krad	0.1567	0.157	0.0003
32	50	Unbiased-50krad	0.1567	0.1569	0.0002
33	50	Unbiased-50krad	0.1499	0.1432	-0.0067
34	50	Unbiased-50krad	0.1567	0.1568	0.0001
40	55	Biased-50krad	0.1502	0.1505	0.0003
41	55	Biased-50krad	0.1497	0.15	0.0003
42	55	Biased-50krad	0.1571	0.1573	0.0002
43	55	Biased-50krad	0.1501	0.1503	0.0002
44	55	Biased-50krad	0.1565	0.1498	-0.0067
45	100	Unbiased-100krad	0.1497	0.1503	0.0006
46	100	Unbiased-100krad	0.1498	0.1434	-0.0064
47	100	Unbiased-100krad	0.1499	0.1505	0.0006
48	100	Unbiased-100krad	0.1505	0.1577	0.0072
49	100	Unbiased-100krad	0.1498	0.1503	0.0005
50	105	Biased-100krad	0.1567	0.1501	-0.0066
51	105	Biased-100krad	0.1497	0.1502	0.0005
52	105	Biased-100krad	0.1503	0.1439	-0.0064
53	105	Biased-100krad	0.1569	0.1575	0.0006
54	105	Biased-100krad	0.1498	0.1503	0.0005

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1499	0.1523	0.157	0.0040706	0.1499	0.1523	0.157	0.0040706	0	0	0	0
30	0.1496	0.15404	0.1569	0.0036212	0.1498	0.15426	0.1573	0.0036432	0.0001	0.00022	0.0004	0.00010954
35	0.1497	0.14976	0.1499	8.9443e-05	0.1499	0.14994	0.15	5.4772e-05	0.0001	0.00018	0.0002	4.4721e-05
50	0.1499	0.15398	0.1567	0.0037245	0.1432	0.15278	0.157	0.0061329	-0.0067	-0.0012	0.0003	0.0030757
55	0.1497	0.15272	0.1571	0.0037352	0.1498	0.15158	0.1573	0.0032089	-0.0067	-0.00114	0.0003	0.0031085
100	0.1497	0.14994	0.1505	0.00032094	0.1434	0.15044	0.1577	0.0050575	-0.0064	0.0005	0.0072	0.0048094
105	0.1497	0.15268	0.1569	0.0037686	0.1439	0.1504	0.1575	0.0048166	-0.0066	-0.00228	0.0006	0.0038532

Device Test: 55.5 _EnSeq|PowerDown/VS3_to_COMP2/3/3///90.9/634//1.8//12/@V_CHANNEL_OFF





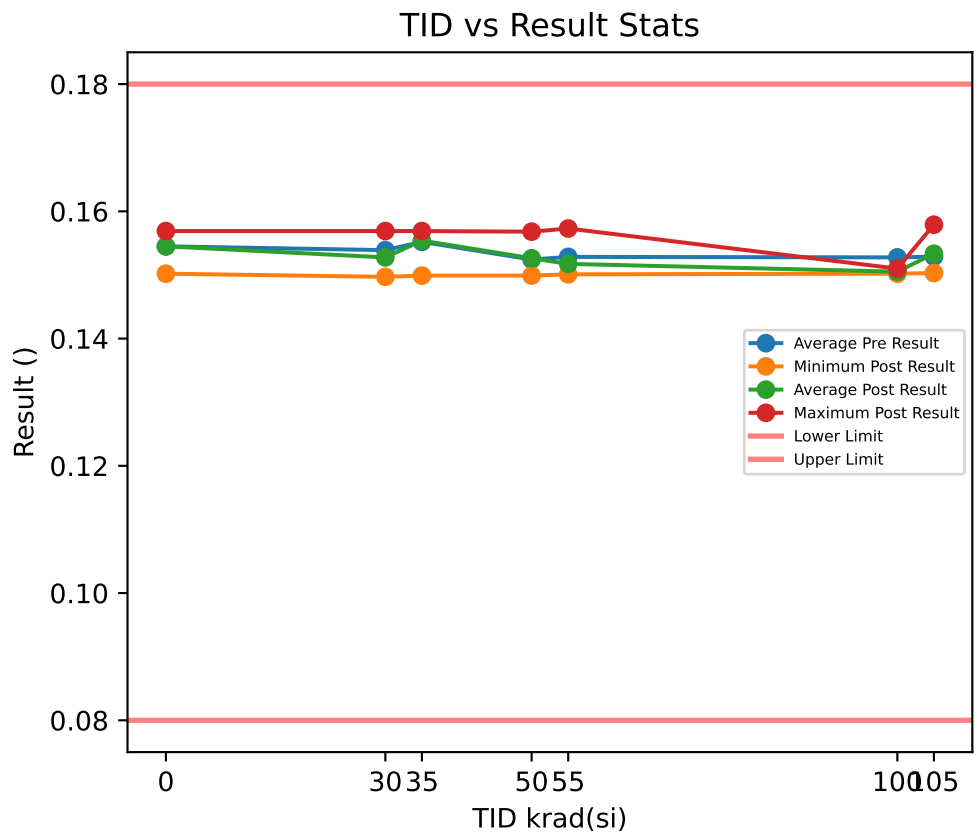
Test Results (Lower Limit = 0.08, Upper Limit = 0.18 ())

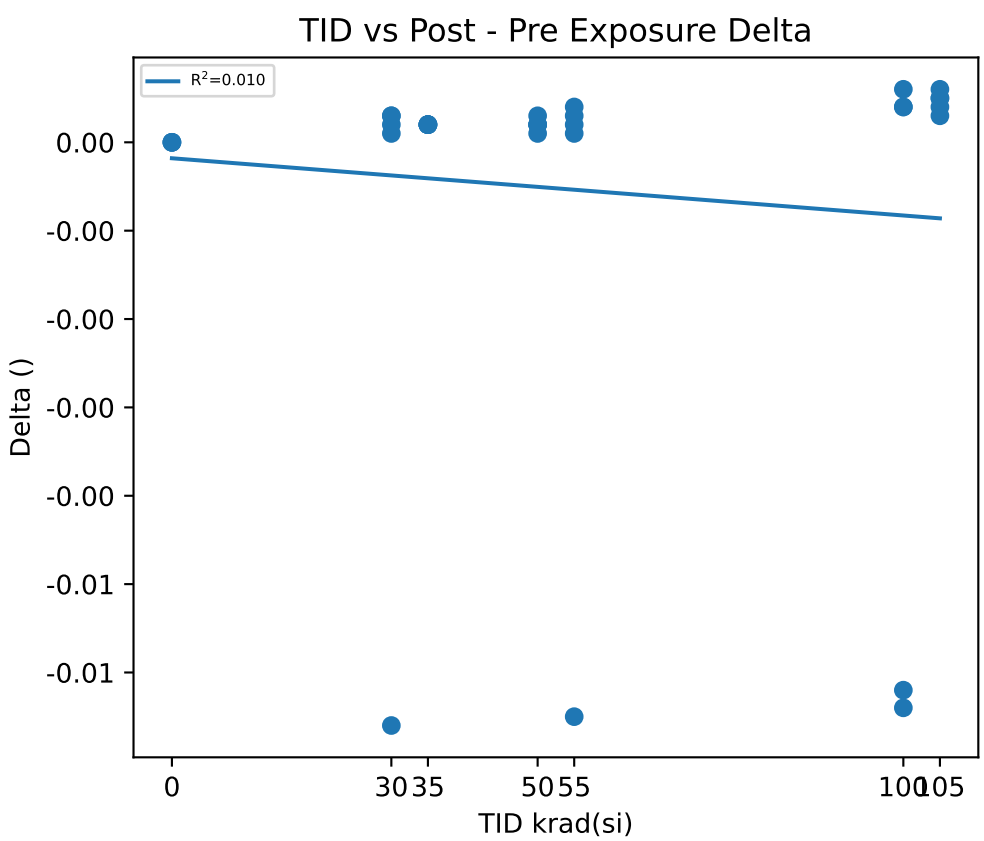
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.15	0.15	0
2	0	CU2	0.157	0.1502	-0.0068
3	0	CU3	0.1496	0.1496	0
11	30	Unbiased-30krad	0.1572	0.1506	-0.0066
12	30	Unbiased-30krad	0.1567	0.1568	0.0001
13	30	Unbiased-30krad	0.1565	0.1499	-0.0066
14	30	Unbiased-30krad	0.1496	0.1499	0.0003
15	30	Unbiased-30krad	0.1498	0.1499	0.0001
16	35	Biased-30krad	0.1499	0.15	0.0001
17	35	Biased-30krad	0.1499	0.1501	0.0002
18	35	Biased-30krad	0.1498	0.15	0.0002
19	35	Biased-30krad	0.1499	0.1501	0.0002
20	35	Biased-30krad	0.1496	0.1498	0.0002
30	50	Unbiased-50krad	0.1497	0.1566	0.0069
31	50	Unbiased-50krad	0.1567	0.157	0.0003
32	50	Unbiased-50krad	0.1496	0.1499	0.0003
33	50	Unbiased-50krad	0.1497	0.1499	0.0002
34	50	Unbiased-50krad	0.1567	0.1569	0.0002
40	55	Biased-50krad	0.1502	0.1505	0.0003
41	55	Biased-50krad	0.1496	0.1499	0.0003
42	55	Biased-50krad	0.1569	0.1572	0.0003
43	55	Biased-50krad	0.1499	0.1501	0.0002
44	55	Biased-50krad	0.1564	0.1565	0.0001
45	100	Unbiased-100krad	0.1566	0.1572	0.0006
46	100	Unbiased-100krad	0.1566	0.157	0.0004
47	100	Unbiased-100krad	0.1498	0.1504	0.0006
48	100	Unbiased-100krad	0.1573	0.1509	-0.0064
49	100	Unbiased-100krad	0.1563	0.1568	0.0005
50	105	Biased-100krad	0.1497	0.15	0.0003
51	105	Biased-100krad	0.1567	0.1505	-0.0062
52	105	Biased-100krad	0.1502	0.1575	0.0073
53	105	Biased-100krad	0.1433	0.1439	0.0006
54	105	Biased-100krad	0.1566	0.1571	0.0005

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1496	0.1522	0.157	0.0041617	0.1496	0.14993	0.1502	0.00030551	-0.0068	-0.0022667	0	0.003926
30	0.1496	0.15396	0.1572	0.0038978	0.1499	0.15142	0.1568	0.0030227	-0.0066	-0.00254	0.0003	0.0037072
35	0.1496	0.14982	0.1499	0.00013038	0.1498	0.15	0.1501	0.00012247	0.0001	0.00018	0.0002	4.4721e-05
50	0.1496	0.15248	0.1567	0.0038525	0.1499	0.15406	0.157	0.0038004	0.0002	0.00158	0.0069	0.0029744
55	0.1496	0.1526	0.1569	0.0037074	0.1499	0.15284	0.1572	0.0036753	0.0001	0.00024	0.0003	8.9443e-05
100	0.1498	0.15532	0.1573	0.0031076	0.1504	0.15446	0.1572	0.0034854	-0.0064	-0.00086	0.0006	0.0030981
105	0.1433	0.1513	0.1567	0.0055906	0.1439	0.1518	0.1575	0.0056551	-0.0062	0.0005	0.0073	0.0047744

Device Test: 55.6 _EnSeq|PowerDown/VS2_to_COMP1/3/3///90.9/634//1.8//12/@V_CHANNEL_OFF





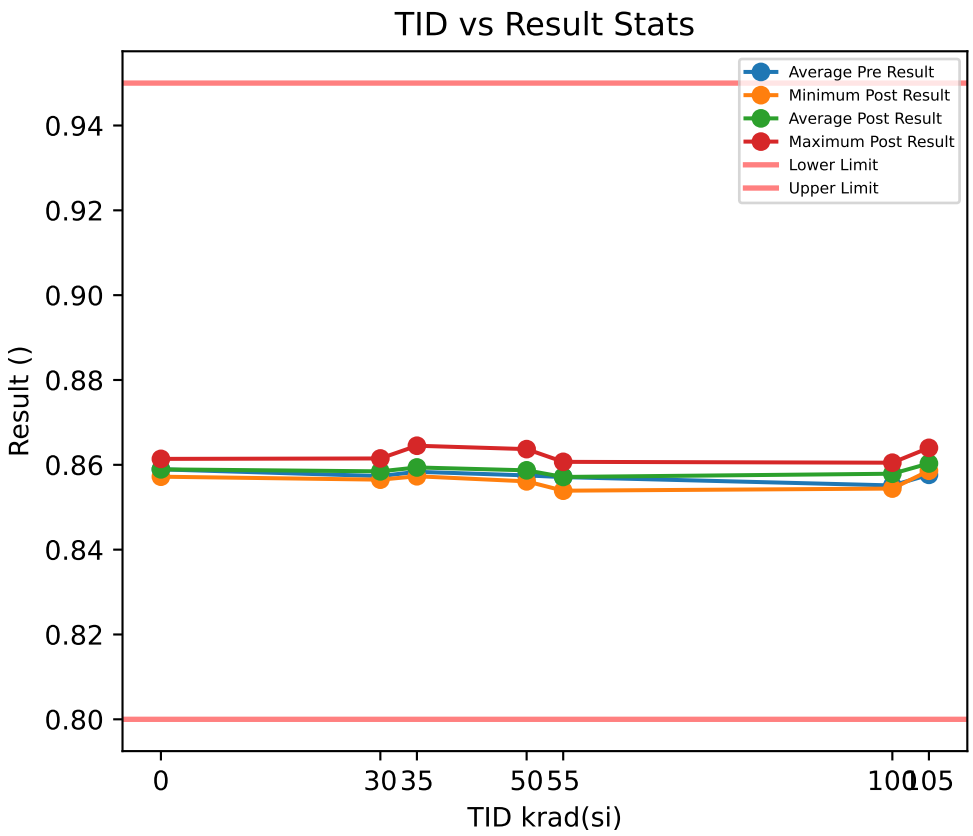
Test Results (Lower Limit = 0.08, Upper Limit = 0.18 ())

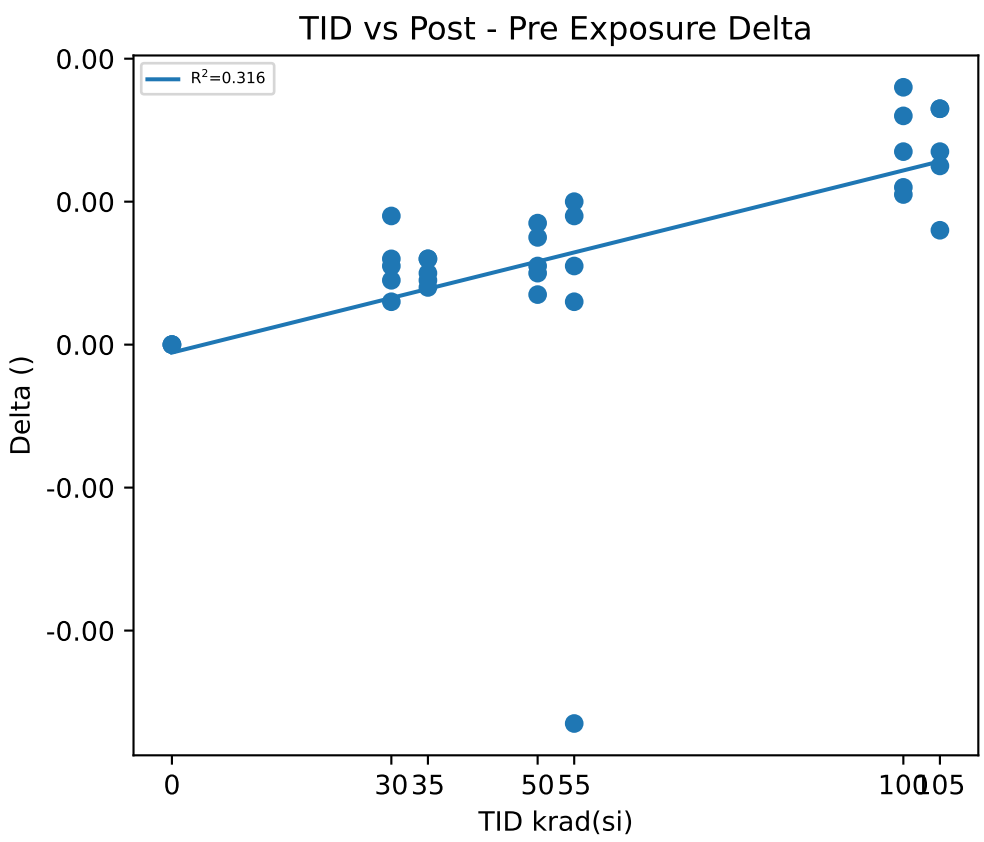
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.1502	0.1502	0
2	0	CU2	0.1569	0.1569	0
3	0	CU3	0.1564	0.1564	0
11	30	Unbiased-30krad	0.1571	0.1505	-0.0066
12	30	Unbiased-30krad	0.1495	0.1497	0.0002
13	30	Unbiased-30krad	0.1566	0.1569	0.0003
14	30	Unbiased-30krad	0.1566	0.1569	0.0003
15	30	Unbiased-30krad	0.1497	0.1498	0.0001
16	35	Biased-30krad	0.1567	0.1569	0.0002
17	35	Biased-30krad	0.1566	0.1568	0.0002
18	35	Biased-30krad	0.1564	0.1566	0.0002
19	35	Biased-30krad	0.1566	0.1568	0.0002
20	35	Biased-30krad	0.1497	0.1499	0.0002
30	50	Unbiased-50krad	0.1565	0.1566	0.0001
31	50	Unbiased-50krad	0.1497	0.1499	0.0002
32	50	Unbiased-50krad	0.1496	0.1499	0.0003
33	50	Unbiased-50krad	0.1497	0.1499	0.0002
34	50	Unbiased-50krad	0.1566	0.1568	0.0002
40	55	Biased-50krad	0.1502	0.1506	0.0004
41	55	Biased-50krad	0.1566	0.1501	-0.0065
42	55	Biased-50krad	0.1503	0.1506	0.0003
43	55	Biased-50krad	0.1571	0.1573	0.0002
44	55	Biased-50krad	0.15	0.1501	0.0001
45	100	Unbiased-100krad	0.1567	0.1505	-0.0062
46	100	Unbiased-100krad	0.1498	0.1502	0.0004
47	100	Unbiased-100krad	0.1499	0.1505	0.0006
48	100	Unbiased-100krad	0.1506	0.151	0.0004
49	100	Unbiased-100krad	0.1568	0.1504	-0.0064
50	105	Biased-100krad	0.15	0.1503	0.0003
51	105	Biased-100krad	0.1499	0.1504	0.0005
52	105	Biased-100krad	0.1502	0.1507	0.0005
53	105	Biased-100krad	0.1573	0.1579	0.0006
54	105	Biased-100krad	0.157	0.1574	0.0004

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1502	0.1545	0.1569	0.0037323	0.1502	0.1545	0.1569	0.0037323	0	0	0	0
30	0.1495	0.1539	0.1571	0.0039313	0.1497	0.15276	0.1569	0.0037918	-0.0066	-0.00114	0.0003	0.0030534
35	0.1497	0.1552	0.1567	0.0030765	0.1499	0.1554	0.1569	0.0030765	0.0002	0.0002	0.0002	1.2415e-17
50	0.1496	0.15242	0.1566	0.0037705	0.1499	0.15262	0.1568	0.0037252	0.0001	0.0002	0.0003	7.0711e-05
55	0.15	0.15284	0.1571	0.0036665	0.1501	0.15174	0.1573	0.0031182	-0.0065	-0.0011	0.0004	0.0030208
100	0.1498	0.15276	0.1568	0.0036555	0.1502	0.15052	0.151	0.00029496	-0.0064	-0.00224	0.0006	0.0037078
105	0.1499	0.15288	0.1573	0.0039009	0.1503	0.15334	0.1579	0.0039412	0.0003	0.00046	0.0006	0.00011402

Device Test: 56.1 _EnSeq|PowerUp/VS1_to_COMP2/7/7///90.9/634//1.8//12/@V_CHANNEL_ON





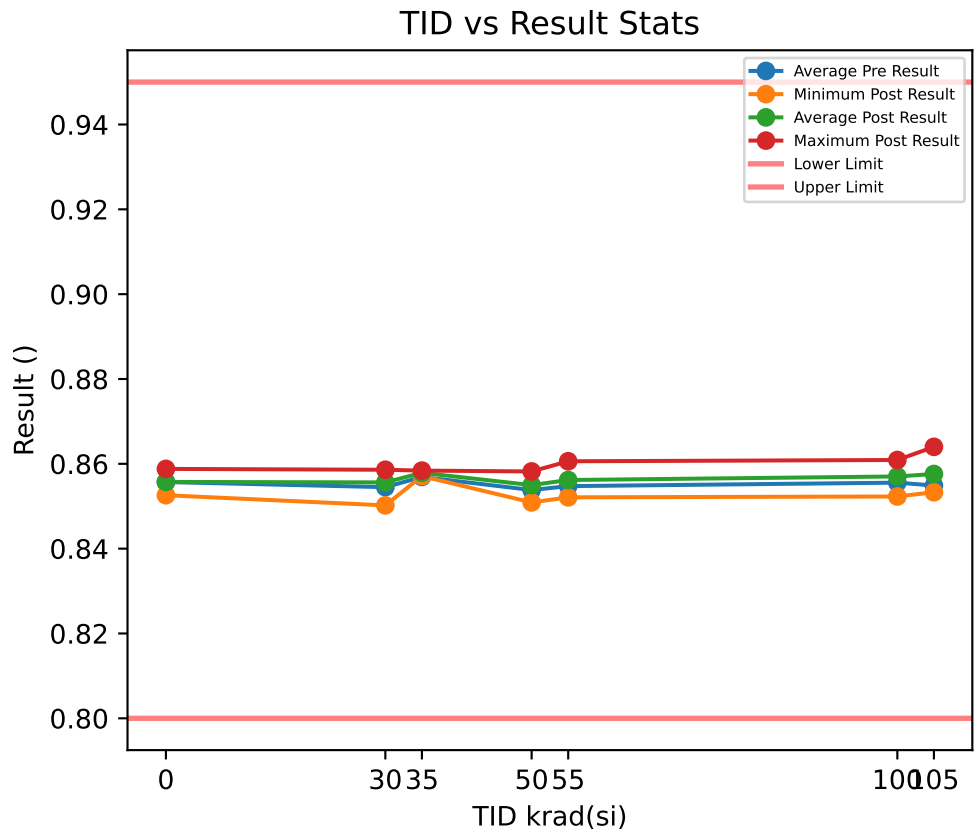
Test Results (Lower Limit = 0.8, Upper Limit = 0.95 ())

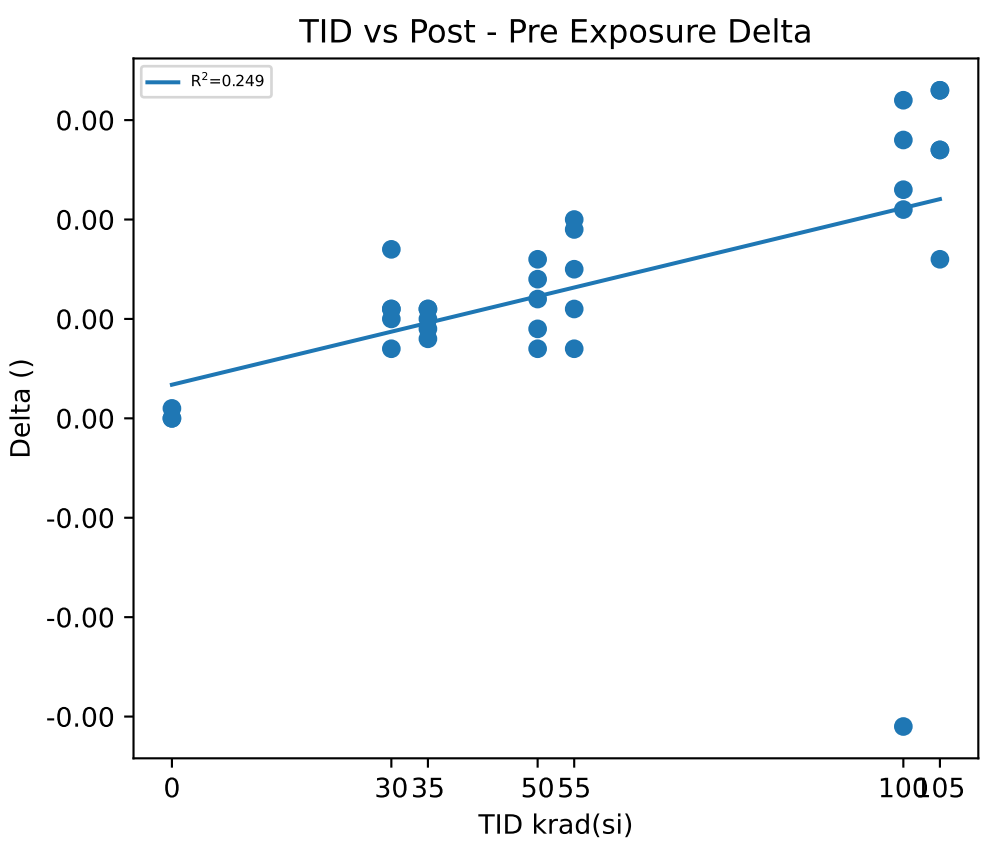
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.8572	0.8572	0
2	0	CU2	0.8614	0.8614	0
3	0	CU3	0.8582	0.8582	0
11	30	Unbiased-30krad	0.8599	0.8611	0.0012
12	30	Unbiased-30krad	0.8557	0.8566	0.0009
13	30	Unbiased-30krad	0.8555	0.8566	0.0011
14	30	Unbiased-30krad	0.8597	0.8615	0.0018
15	30	Unbiased-30krad	0.8559	0.8565	0.0006
16	35	Biased-30krad	0.8637	0.8645	0.0008
17	35	Biased-30krad	0.8567	0.8576	0.0009
18	35	Biased-30krad	0.8581	0.8593	0.0012
19	35	Biased-30krad	0.8561	0.8573	0.0012
20	35	Biased-30krad	0.8572	0.8582	0.001
30	50	Unbiased-50krad	0.8554	0.8561	0.0007
31	50	Unbiased-50krad	0.8562	0.8577	0.0015
32	50	Unbiased-50krad	0.862	0.8637	0.0017
33	50	Unbiased-50krad	0.8564	0.8575	0.0011
34	50	Unbiased-50krad	0.8575	0.8585	0.001
40	55	Biased-50krad	0.8587	0.8607	0.002
41	55	Biased-50krad	0.8583	0.8601	0.0018
42	55	Biased-50krad	0.8598	0.8545	-0.0053
43	55	Biased-50krad	0.8528	0.8539	0.0011
44	55	Biased-50krad	0.8559	0.8565	0.0006
45	100	Unbiased-100krad	0.8512	0.8544	0.0032
46	100	Unbiased-100krad	0.8565	0.8586	0.0021
47	100	Unbiased-100krad	0.8569	0.8605	0.0036
48	100	Unbiased-100krad	0.8539	0.8561	0.0022
49	100	Unbiased-100krad	0.8572	0.8599	0.0027
50	105	Biased-100krad	0.857	0.8586	0.0016
51	105	Biased-100krad	0.8559	0.8592	0.0033
52	105	Biased-100krad	0.8572	0.8599	0.0027
53	105	Biased-100krad	0.8607	0.864	0.0033
54	105	Biased-100krad	0.8574	0.8599	0.0025

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.8572	0.85893	0.8614	0.0021939	0.8572	0.85893	0.8614	0.0021939	0	0	0	0
30	0.8555	0.85734	0.8599	0.0022512	0.8565	0.85846	0.8615	0.0025967	0.0006	0.00112	0.0018	0.00044385
35	0.8561	0.85836	0.8637	0.0030738	0.8573	0.85938	0.8645	0.0029626	0.0008	0.00102	0.0012	0.00017889
50	0.8554	0.8575	0.862	0.0026249	0.8561	0.8587	0.8637	0.0029257	0.0007	0.0012	0.0017	0.0004
55	0.8528	0.8571	0.8598	0.0027937	0.8539	0.85714	0.8607	0.003135	-0.0053	4e-05	0.002	0.0030369
100	0.8512	0.85514	0.8572	0.0025618	0.8544	0.8579	0.8605	0.0025855	0.0021	0.00276	0.0036	0.00064265
105	0.8559	0.85764	0.8607	0.0018064	0.8586	0.86032	0.864	0.0021277	0.0016	0.00268	0.0033	0.00070143

Device Test: 56.2 _EnSeq|PowerUp/VS2_to_COMP3/7/7///90.9/634//1.8//12/@V_CHANNEL_ON





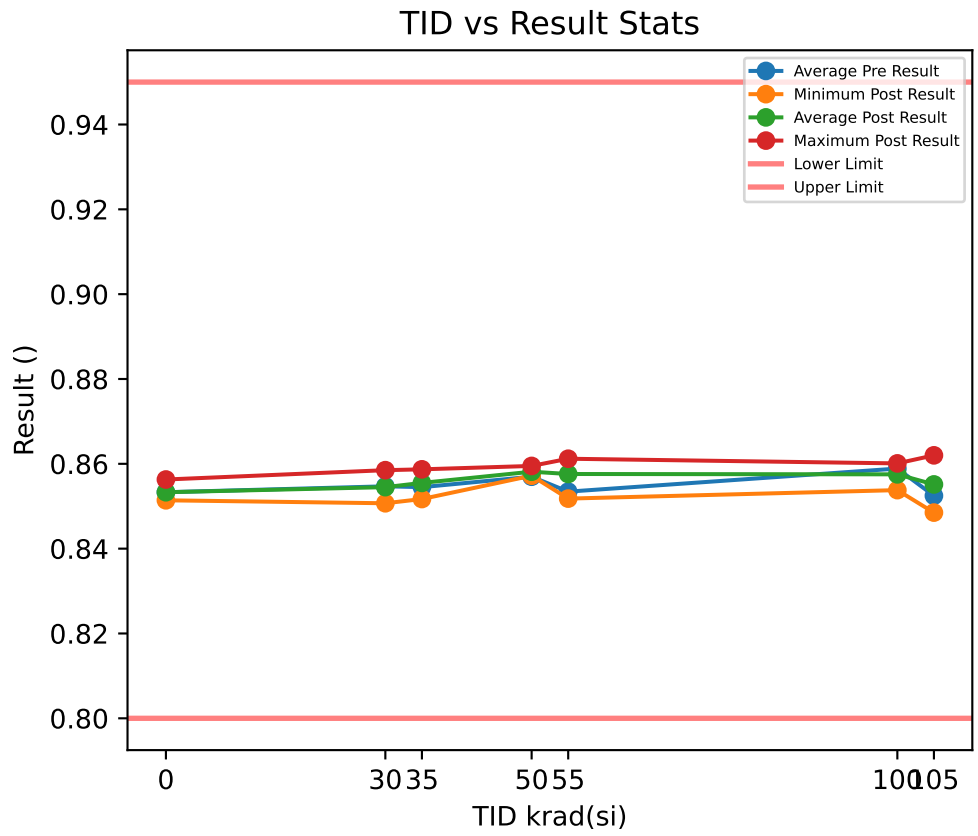
Test Results (Lower Limit = 0.8, Upper Limit = 0.95 ())

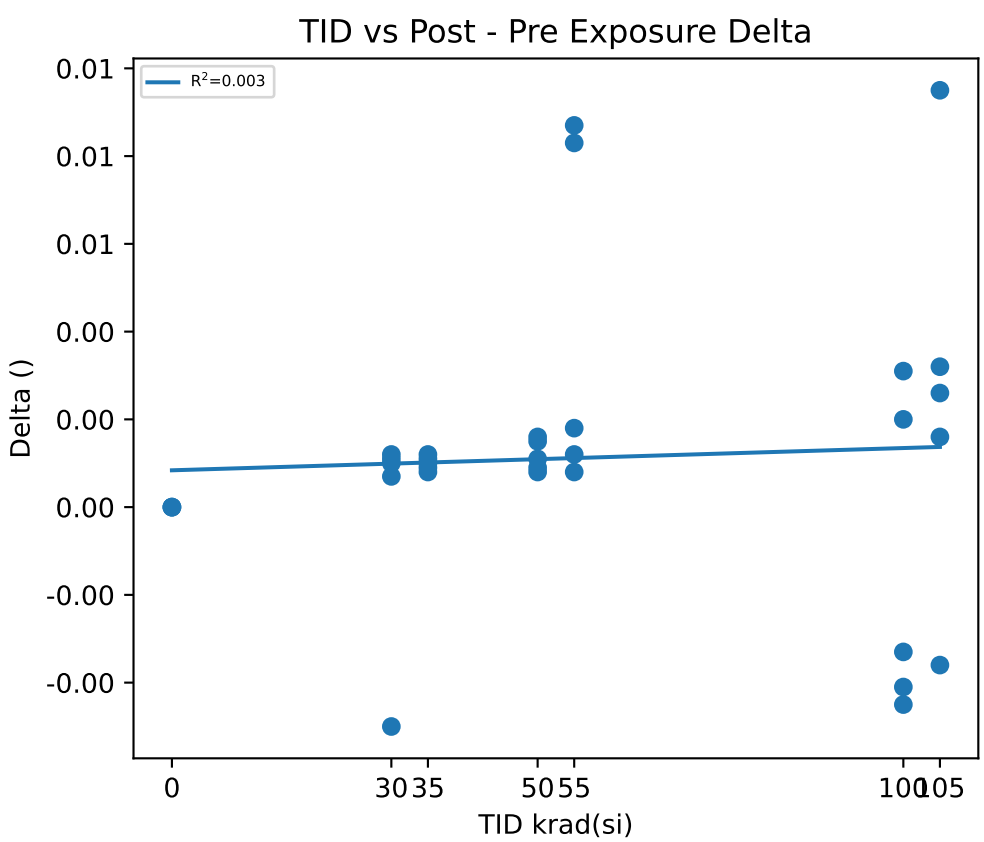
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.8526	0.8526	0
2	0	CU2	0.8587	0.8588	0.0001
3	0	CU3	0.8558	0.8558	0
11	30	Unbiased-30krad	0.8532	0.8543	0.0011
12	30	Unbiased-30krad	0.8555	0.8565	0.001
13	30	Unbiased-30krad	0.8574	0.8585	0.0011
14	30	Unbiased-30krad	0.8569	0.8586	0.0017
15	30	Unbiased-30krad	0.8495	0.8502	0.0007
16	35	Biased-30krad	0.8575	0.8583	0.0008
17	35	Biased-30krad	0.857	0.8579	0.0009
18	35	Biased-30krad	0.856	0.8571	0.0011
19	35	Biased-30krad	0.8573	0.8584	0.0011
20	35	Biased-30krad	0.8567	0.8577	0.001
30	50	Unbiased-50krad	0.8564	0.8571	0.0007
31	50	Unbiased-50krad	0.8498	0.8512	0.0014
32	50	Unbiased-50krad	0.8559	0.8575	0.0016
33	50	Unbiased-50krad	0.8497	0.8509	0.0012
34	50	Unbiased-50krad	0.8573	0.8582	0.0009
40	55	Biased-50krad	0.8528	0.8548	0.002
41	55	Biased-50krad	0.857	0.8589	0.0019
42	55	Biased-50krad	0.853	0.8545	0.0015
43	55	Biased-50krad	0.8595	0.8606	0.0011
44	55	Biased-50krad	0.8514	0.8521	0.0007
45	100	Unbiased-100krad	0.8577	0.8609	0.0032
46	100	Unbiased-100krad	0.8502	0.8523	0.0021
47	100	Unbiased-100krad	0.8574	0.8543	-0.0031
48	100	Unbiased-100krad	0.8545	0.8568	0.0023
49	100	Unbiased-100krad	0.858	0.8608	0.0028
50	105	Biased-100krad	0.8517	0.8533	0.0016
51	105	Biased-100krad	0.8505	0.8538	0.0033
52	105	Biased-100krad	0.8525	0.8552	0.0027
53	105	Biased-100krad	0.8607	0.864	0.0033
54	105	Biased-100krad	0.859	0.8617	0.0027

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.8526	0.8557	0.8587	0.0030512	0.8526	0.85573	0.8588	0.0031005	0	3.3333e-05	0.0001	5.7735e-05
30	0.8495	0.8545	0.8574	0.003235	0.8502	0.85562	0.8586	0.0035024	0.0007	0.00112	0.0017	0.00036332
35	0.856	0.8569	0.8575	0.00058737	0.8571	0.85788	0.8584	0.00052154	0.0008	0.00098	0.0011	0.00013038
50	0.8497	0.85382	0.8573	0.0037493	0.8509	0.85498	0.8582	0.0036107	0.0007	0.00116	0.0016	0.00036469
55	0.8514	0.85474	0.8595	0.0033805	0.8521	0.85618	0.8606	0.0034752	0.0007	0.00144	0.002	0.00054589
100	0.8502	0.85556	0.858	0.003308	0.8523	0.85702	0.8609	0.0038428	-0.0031	0.00146	0.0032	0.0025851
105	0.8505	0.85488	0.8607	0.0046316	0.8533	0.8576	0.864	0.0049107	0.0016	0.00272	0.0033	0.00069426

Device Test: 56.3 _EnSeq|PowerUp/VS3_to_COMP4/7/7///90.9/634//1.8//12/@V_CHANNEL_ON





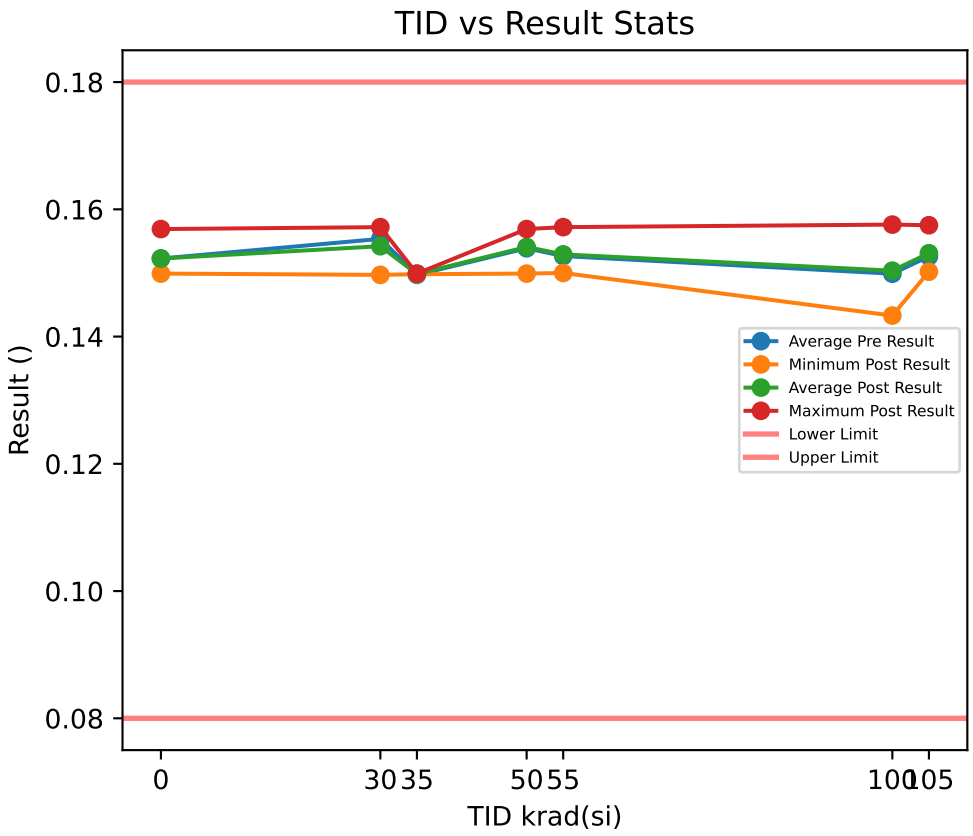
Test Results (Lower Limit = 0.8, Upper Limit = 0.95 ())

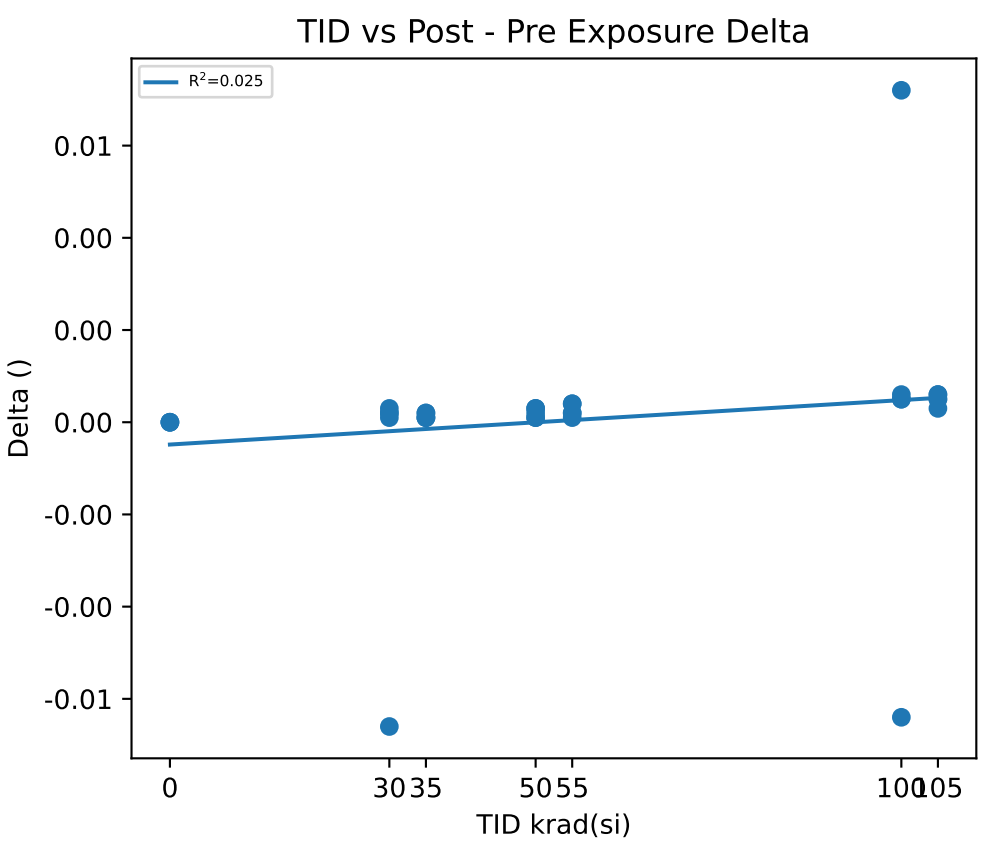
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.8514	0.8514	0
2	0	CU2	0.8522	0.8522	0
3	0	CU3	0.8563	0.8563	0
11	30	Unbiased-30krad	0.8536	0.8548	0.0012
12	30	Unbiased-30krad	0.8575	0.8585	0.001
13	30	Unbiased-30krad	0.8565	0.8576	0.0011
14	30	Unbiased-30krad	0.8557	0.8507	-0.005
15	30	Unbiased-30krad	0.8502	0.8509	0.0007
16	35	Biased-30krad	0.8575	0.8583	0.0008
17	35	Biased-30krad	0.851	0.8519	0.0009
18	35	Biased-30krad	0.8506	0.8517	0.0011
19	35	Biased-30krad	0.8575	0.8587	0.0012
20	35	Biased-30krad	0.8559	0.8569	0.001
30	50	Unbiased-50krad	0.8564	0.8572	0.0008
31	50	Unbiased-50krad	0.858	0.8595	0.0015
32	50	Unbiased-50krad	0.8559	0.8575	0.0016
33	50	Unbiased-50krad	0.8568	0.8579	0.0011
34	50	Unbiased-50krad	0.8577	0.8586	0.0009
40	55	Biased-50krad	0.8525	0.8612	0.0087
41	55	Biased-50krad	0.8561	0.8579	0.0018
42	55	Biased-50krad	0.852	0.8603	0.0083
43	55	Biased-50krad	0.8506	0.8518	0.0012
44	55	Biased-50krad	0.856	0.8568	0.0008
45	100	Unbiased-100krad	0.857	0.8601	0.0031
46	100	Unbiased-100krad	0.8571	0.8591	0.002
47	100	Unbiased-100krad	0.8571	0.8538	-0.0033
48	100	Unbiased-100krad	0.8607	0.8562	-0.0045
49	100	Unbiased-100krad	0.8625	0.8584	-0.0041
50	105	Biased-100krad	0.8499	0.8515	0.0016
51	105	Biased-100krad	0.8575	0.8539	-0.0036
52	105	Biased-100krad	0.8525	0.862	0.0095
53	105	Biased-100krad	0.8453	0.8485	0.0032
54	105	Biased-100krad	0.8572	0.8598	0.0026

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.8514	0.8533	0.8563	0.0026287	0.8514	0.8533	0.8563	0.0026287	0	0	0	0
30	0.8502	0.8547	0.8575	0.0028957	0.8507	0.8545	0.8585	0.0036435	-0.005	-0.0002	0.0012	0.0026898
35	0.8506	0.8545	0.8575	0.0034431	0.8517	0.8555	0.8587	0.0034438	0.0008	0.001	0.0012	0.00015811
50	0.8559	0.85696	0.858	0.0008792	0.8572	0.85814	0.8595	0.00092358	0.0008	0.00118	0.0016	0.00035637
55	0.8506	0.85344	0.8561	0.0024825	0.8518	0.8576	0.8612	0.0036953	0.0008	0.00416	0.0087	0.0039803
100	0.857	0.85888	0.8625	0.0025636	0.8538	0.85752	0.8601	0.0025253	-0.0045	-0.00136	0.0031	0.0036164
105	0.8453	0.85248	0.8575	0.0051402	0.8485	0.85514	0.862	0.0056492	-0.0036	0.00266	0.0095	0.0046742

Device Test: 56.4 _EnSeq|PowerDown/VS4_to_COMP3/7/7///90.9/634//1.8//12/@V_CHANNEL_OFF





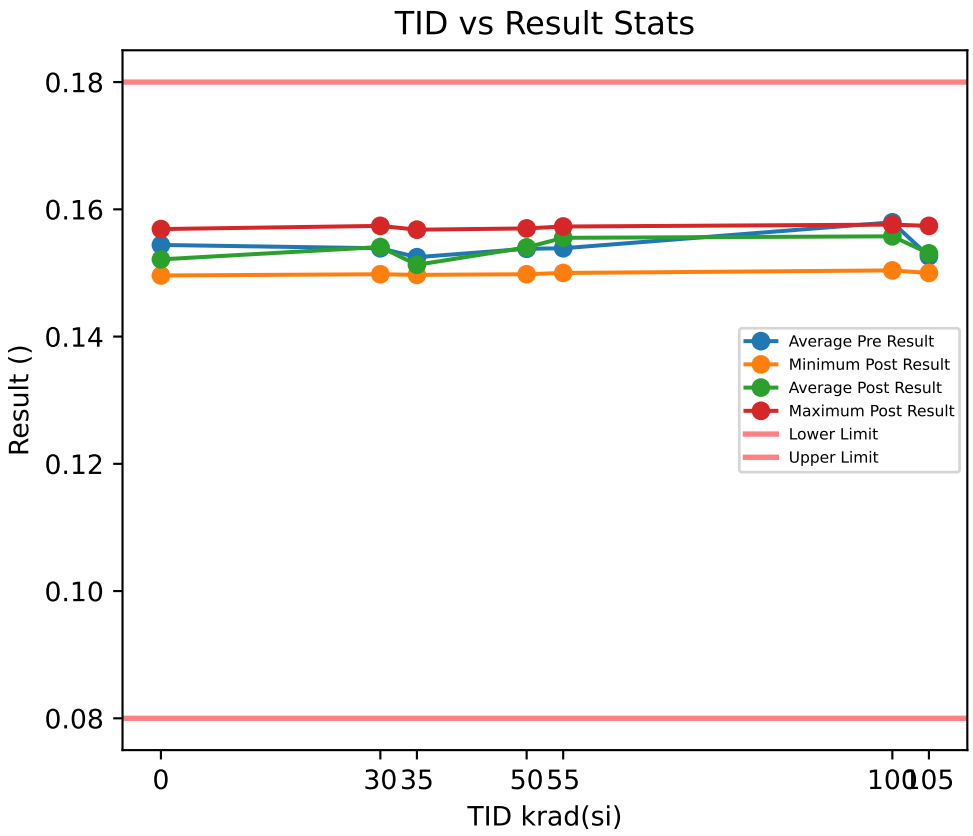
Test Results (Lower Limit = 0.08, Upper Limit = 0.18 ())

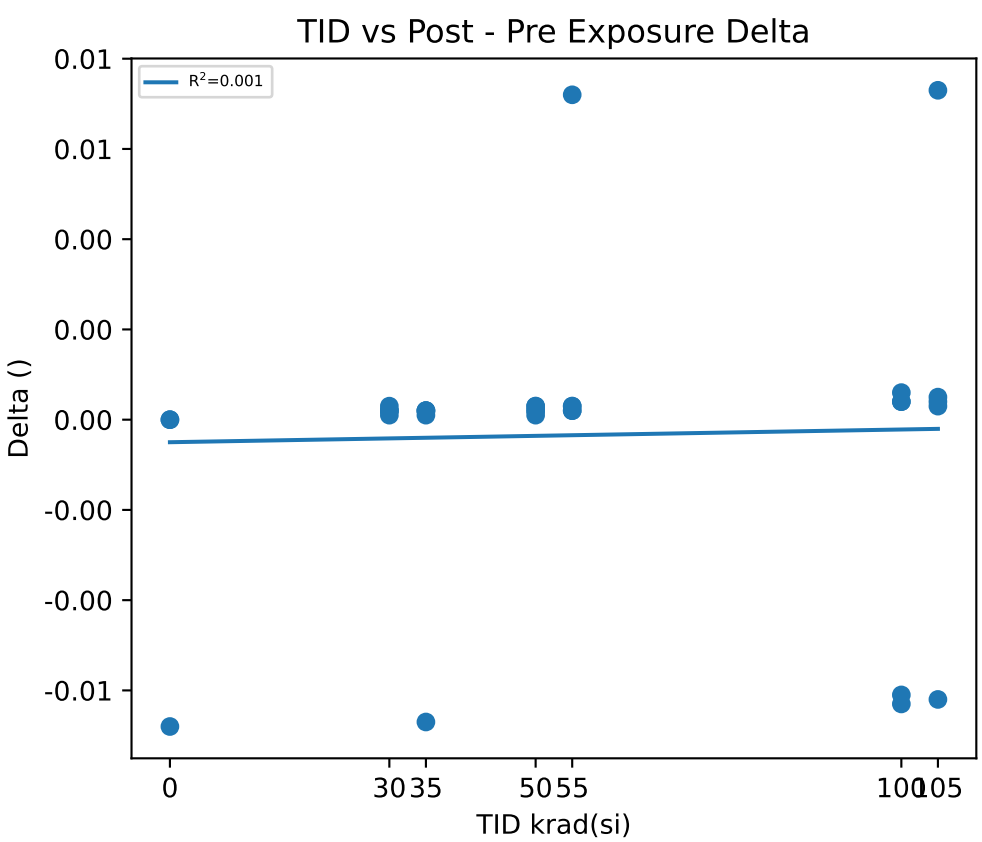
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.15	0.15	0
2	0	CU2	0.1569	0.1569	0
3	0	CU3	0.1499	0.1499	0
11	30	Unbiased-30krad	0.1574	0.1508	-0.0066
12	30	Unbiased-30krad	0.1563	0.1564	0.0001
13	30	Unbiased-30krad	0.1495	0.1497	0.0002
14	30	Unbiased-30krad	0.1569	0.1572	0.0003
15	30	Unbiased-30krad	0.1567	0.1569	0.0002
16	35	Biased-30krad	0.1498	0.1499	0.0001
17	35	Biased-30krad	0.1497	0.1498	0.0001
18	35	Biased-30krad	0.1496	0.1498	0.0002
19	35	Biased-30krad	0.1497	0.1499	0.0002
20	35	Biased-30krad	0.1497	0.1498	0.0001
30	50	Unbiased-50krad	0.1498	0.1499	0.0001
31	50	Unbiased-50krad	0.1566	0.1569	0.0003
32	50	Unbiased-50krad	0.1566	0.1569	0.0003
33	50	Unbiased-50krad	0.1498	0.15	0.0002
34	50	Unbiased-50krad	0.1566	0.1567	0.0001
40	55	Biased-50krad	0.1501	0.1505	0.0004
41	55	Biased-50krad	0.1496	0.15	0.0004
42	55	Biased-50krad	0.157	0.1572	0.0002
43	55	Biased-50krad	0.1501	0.1503	0.0002
44	55	Biased-50krad	0.1565	0.1566	0.0001
45	100	Unbiased-100krad	0.1497	0.1502	0.0005
46	100	Unbiased-100krad	0.1497	0.1433	-0.0064
47	100	Unbiased-100krad	0.1499	0.1505	0.0006
48	100	Unbiased-100krad	0.1504	0.1576	0.0072
49	100	Unbiased-100krad	0.1497	0.1502	0.0005
50	105	Biased-100krad	0.1566	0.1569	0.0003
51	105	Biased-100krad	0.1496	0.1502	0.0006
52	105	Biased-100krad	0.1502	0.1507	0.0005
53	105	Biased-100krad	0.1569	0.1575	0.0006
54	105	Biased-100krad	0.1497	0.1502	0.0005

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1499	0.15227	0.1569	0.0040129	0.1499	0.15227	0.1569	0.0040129	0	0	0	0
30	0.1495	0.15536	0.1574	0.0032997	0.1497	0.1542	0.1572	0.003638	-0.0066	-0.00116	0.0003	0.0030419
35	0.1496	0.1497	0.1498	7.0711e-05	0.1498	0.14984	0.1499	5.4772e-05	0.0001	0.00014	0.0002	5.4772e-05
50	0.1498	0.15388	0.1566	0.0037245	0.1499	0.15408	0.1569	0.0037712	0.0001	0.0002	0.0003	0.0001
55	0.1496	0.15266	0.157	0.0037434	0.15	0.15292	0.1572	0.0036438	0.0001	0.00026	0.0004	0.00013416
100	0.1497	0.14988	0.1504	0.00030332	0.1433	0.15036	0.1576	0.005058	-0.0064	0.00048	0.0072	0.0048091
105	0.1496	0.1526	0.1569	0.0037967	0.1502	0.1531	0.1575	0.0037543	0.0003	0.0005	0.0006	0.00012247

Device Test: 56.5 _EnSeq|PowerDown/VS3_to_COMP2/7/7///90.9/634//1.8//12/@V_CHANNEL_OFF





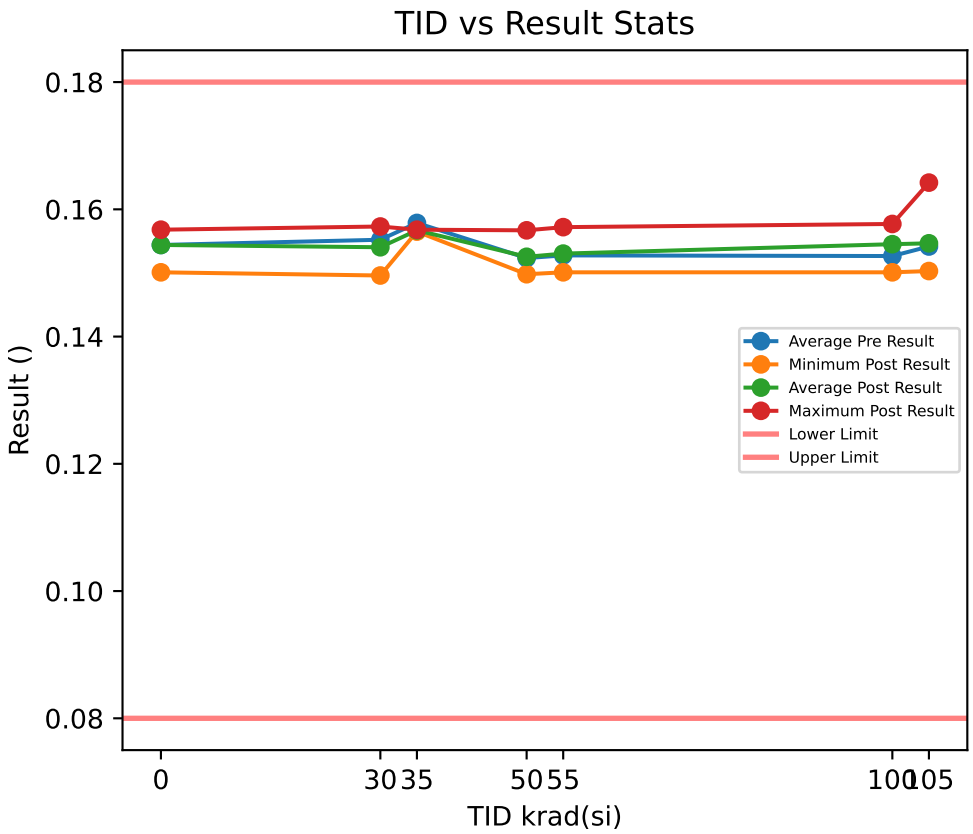
Test Results (Lower Limit = 0.08, Upper Limit = 0.18 ())

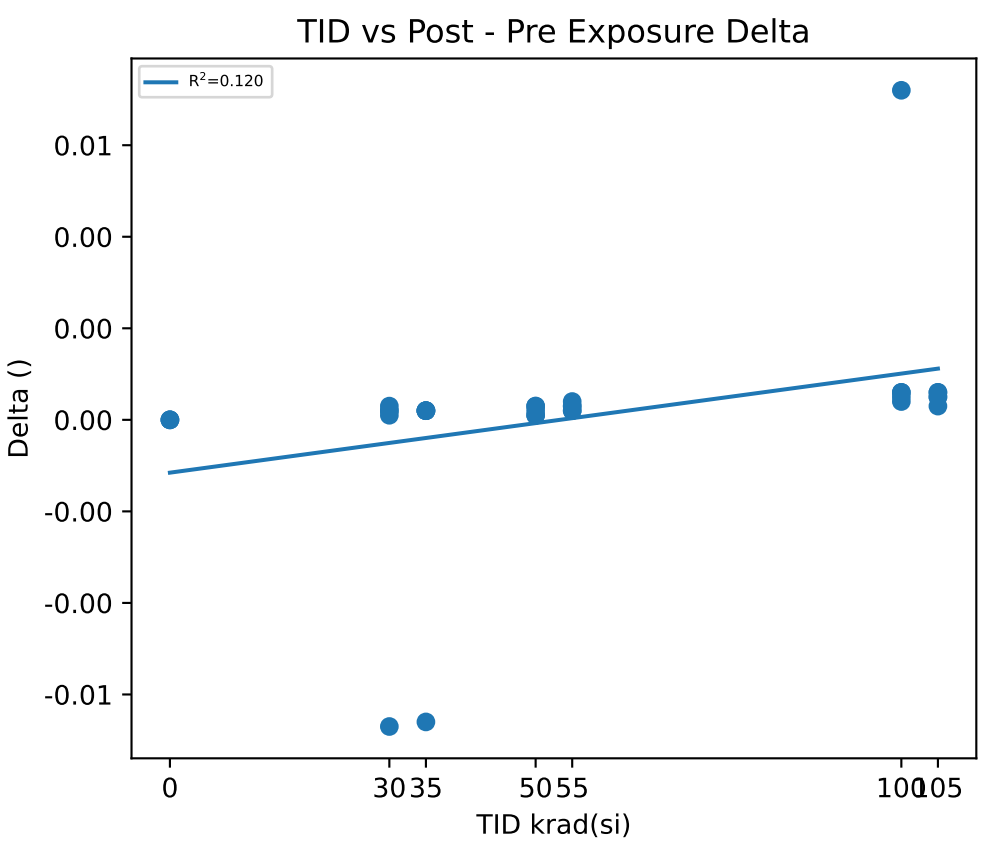
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.1499	0.1499	0
2	0	CU2	0.1569	0.1569	0
3	0	CU3	0.1564	0.1496	-0.0068
11	30	Unbiased-30krad	0.1572	0.1574	0.0002
12	30	Unbiased-30krad	0.1566	0.1568	0.0002
13	30	Unbiased-30krad	0.1564	0.1566	0.0002
14	30	Unbiased-30krad	0.1495	0.1498	0.0003
15	30	Unbiased-30krad	0.1497	0.1498	0.0001
16	35	Biased-30krad	0.1566	0.1499	-0.0067
17	35	Biased-30krad	0.1499	0.15	0.0001
18	35	Biased-30krad	0.1498	0.15	0.0002
19	35	Biased-30krad	0.1566	0.1568	0.0002
20	35	Biased-30krad	0.1495	0.1497	0.0002
30	50	Unbiased-50krad	0.1564	0.1566	0.0002
31	50	Unbiased-50krad	0.1567	0.157	0.0003
32	50	Unbiased-50krad	0.1495	0.1498	0.0003
33	50	Unbiased-50krad	0.1497	0.1499	0.0002
34	50	Unbiased-50krad	0.1567	0.1568	0.0001
40	55	Biased-50krad	0.1501	0.1573	0.0072
41	55	Biased-50krad	0.1564	0.1567	0.0003
42	55	Biased-50krad	0.1568	0.1571	0.0003
43	55	Biased-50krad	0.1498	0.15	0.0002
44	55	Biased-50krad	0.1563	0.1565	0.0002
45	100	Unbiased-100krad	0.1565	0.1571	0.0006
46	100	Unbiased-100krad	0.1565	0.1569	0.0004
47	100	Unbiased-100krad	0.1565	0.1504	-0.0061
48	100	Unbiased-100krad	0.1572	0.1576	0.0004
49	100	Unbiased-100krad	0.1631	0.1568	-0.0063
50	105	Biased-100krad	0.1497	0.15	0.0003
51	105	Biased-100krad	0.1566	0.1504	-0.0062
52	105	Biased-100krad	0.1501	0.1574	0.0073
53	105	Biased-100krad	0.1501	0.1506	0.0005
54	105	Biased-100krad	0.1566	0.157	0.0004

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1499	0.1544	0.1569	0.0039051	0.1496	0.15213	0.1569	0.0041308	-0.0068	-0.0022667	0	0.003926
30	0.1495	0.15388	0.1572	0.0039188	0.1498	0.15408	0.1574	0.0039182	0.0001	0.0002	0.0003	7.0711e-05
35	0.1495	0.15248	0.1566	0.0037639	0.1497	0.15128	0.1568	0.0030882	-0.0067	-0.0012	0.0002	0.0030749
50	0.1495	0.1538	0.1567	0.0038367	0.1498	0.15402	0.157	0.0038095	0.0001	0.00022	0.0003	8.3666e-05
55	0.1498	0.15388	0.1568	0.003594	0.15	0.15552	0.1573	0.0031019	0.0002	0.00164	0.0072	0.0031085
100	0.1565	0.15796	0.1631	0.0028893	0.1504	0.15576	0.1576	0.0030121	-0.0063	-0.0022	0.0006	0.0036531
105	0.1497	0.15262	0.1566	0.0036369	0.15	0.15308	0.1574	0.0037699	-0.0062	0.00046	0.0073	0.0047742

Device Test: 56.6 _EnSeq|PowerDown/VS2_to_COMP1/7/7///90.9/634//1.8//12/@V_CHANNEL_OFF





Test Results (Lower Limit = 0.08, Upper Limit = 0.18 ())

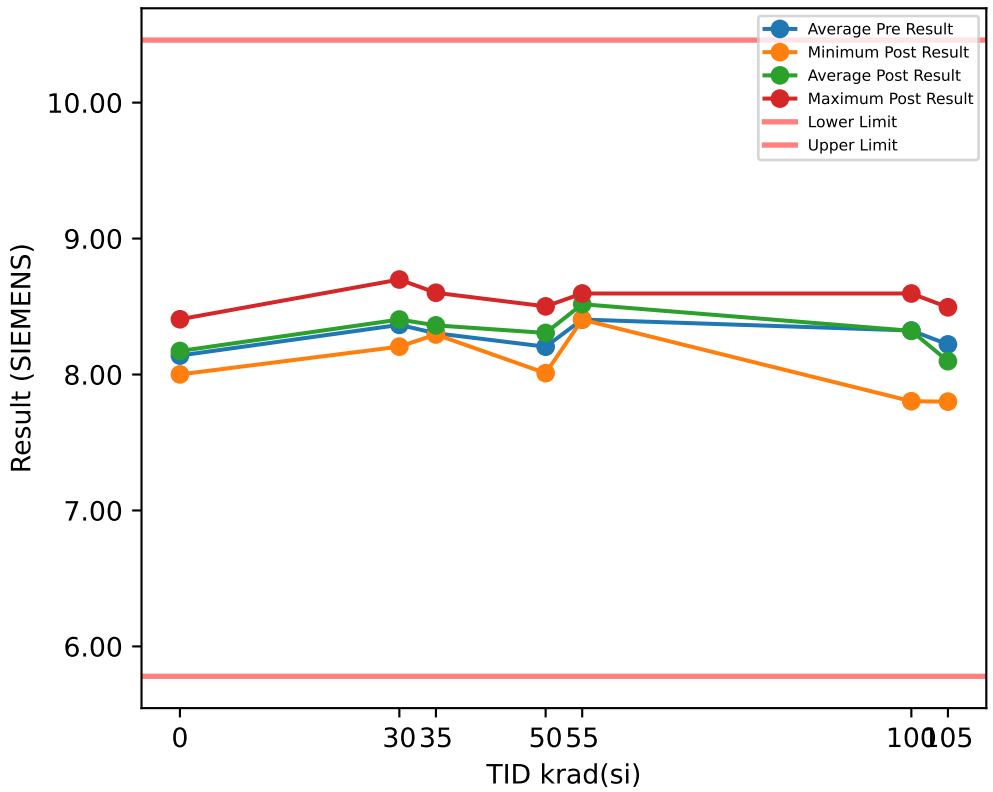
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.1501	0.1501	0
2	0	CU2	0.1568	0.1568	0
3	0	CU3	0.1563	0.1563	0
11	30	Unbiased-30krad	0.1571	0.1573	0.0002
12	30	Unbiased-30krad	0.1563	0.1496	-0.0067
13	30	Unbiased-30krad	0.1566	0.1568	0.0002
14	30	Unbiased-30krad	0.1565	0.1568	0.0003
15	30	Unbiased-30krad	0.1496	0.1497	0.0001
16	35	Biased-30krad	0.1566	0.1568	0.0002
17	35	Biased-30krad	0.1633	0.1567	-0.0066
18	35	Biased-30krad	0.1563	0.1565	0.0002
19	35	Biased-30krad	0.1566	0.1568	0.0002
20	35	Biased-30krad	0.1565	0.1567	0.0002
30	50	Unbiased-50krad	0.1564	0.1565	0.0001
31	50	Unbiased-50krad	0.1496	0.1499	0.0003
32	50	Unbiased-50krad	0.1495	0.1498	0.0003
33	50	Unbiased-50krad	0.1496	0.1498	0.0002
34	50	Unbiased-50krad	0.1566	0.1567	0.0001
40	55	Biased-50krad	0.1502	0.1505	0.0003
41	55	Biased-50krad	0.1565	0.1569	0.0004
42	55	Biased-50krad	0.1502	0.1505	0.0003
43	55	Biased-50krad	0.157	0.1572	0.0002
44	55	Biased-50krad	0.1499	0.1501	0.0002
45	100	Unbiased-100krad	0.1566	0.1572	0.0006
46	100	Unbiased-100krad	0.1497	0.1501	0.0004
47	100	Unbiased-100krad	0.1498	0.1504	0.0006
48	100	Unbiased-100krad	0.1505	0.1577	0.0072
49	100	Unbiased-100krad	0.1567	0.1572	0.0005
50	105	Biased-100krad	0.15	0.1503	0.0003
51	105	Biased-100krad	0.1498	0.1504	0.0006
52	105	Biased-100krad	0.1501	0.1506	0.0005
53	105	Biased-100krad	0.1572	0.1578	0.0006
54	105	Biased-100krad	0.1637	0.1642	0.0005

Test Statistics ()

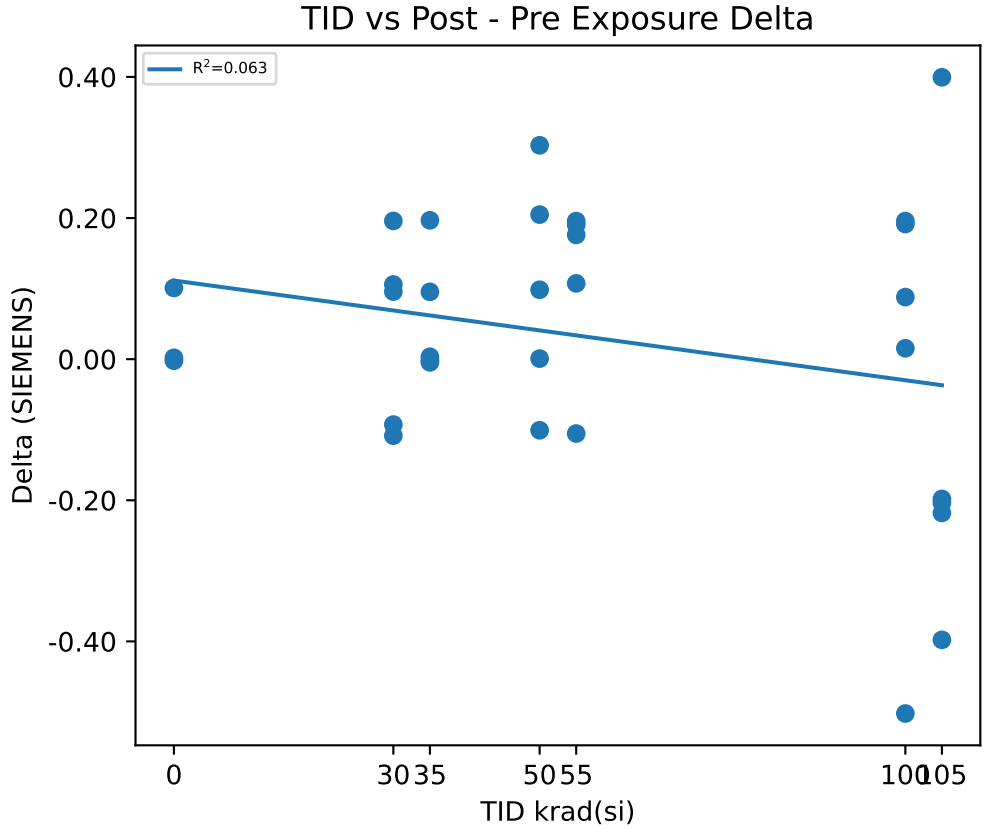
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1501	0.1544	0.1568	0.0037323	0.1501	0.1544	0.1568	0.0037323	0	0	0	0
30	0.1496	0.15522	0.1571	0.0031555	0.1496	0.15404	0.1573	0.0040129	-0.0067	-0.00118	0.0003	0.0030866
35	0.1563	0.15786	0.1633	0.0030435	0.1565	0.1567	0.1568	0.00012247	-0.0066	-0.00116	0.0002	0.0030411
50	0.1495	0.15234	0.1566	0.0037984	0.1498	0.15254	0.1567	0.0037072	0.0001	0.0002	0.0003	0.0001
55	0.1499	0.15276	0.157	0.0036487	0.1501	0.15304	0.1572	0.0036658	0.0002	0.00028	0.0004	8.3666e-05
100	0.1497	0.15266	0.1567	0.0036555	0.1501	0.15452	0.1577	0.0039047	0.0004	0.00186	0.0072	0.0029863
105	0.1498	0.15416	0.1637	0.0061857	0.1503	0.15466	0.1642	0.0062151	0.0003	0.0005	0.0006	0.00012247

Device Test: 68.17 _EA_GMPS|GMPS/CH1/3/3///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

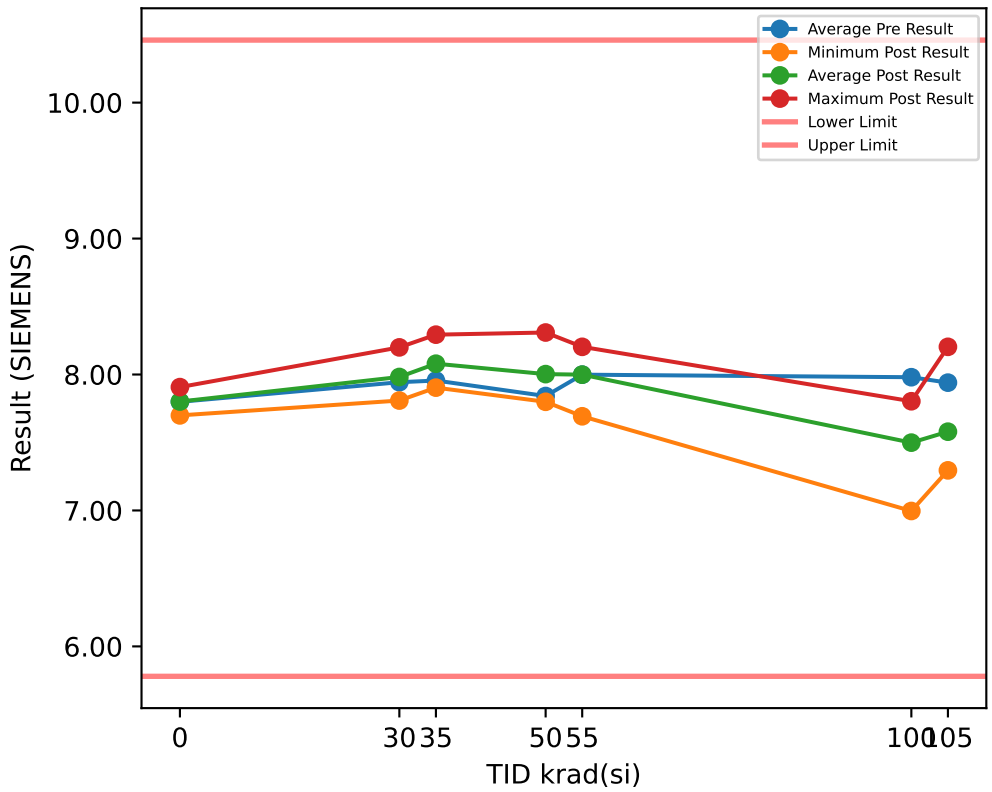
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.003	8.0008	-0.0022
2	0	CU2	8.1095	8.1114	0.0019
3	0	CU3	8.3055	8.4064	0.1009
11	30	Unbiased-30krad	8.5094	8.6052	0.0958
12	30	Unbiased-30krad	8.2989	8.2062	-0.0927
13	30	Unbiased-30krad	8.5028	8.6987	0.1959
14	30	Unbiased-30krad	8.416	8.3076	-0.1084
15	30	Unbiased-30krad	8.099	8.2049	0.1059
16	35	Biased-30krad	8.1108	8.3076	0.1968
17	35	Biased-30krad	8.3068	8.3023	-0.0045
18	35	Biased-30krad	8.291	8.2944	0.0034
19	35	Biased-30krad	8.6027	8.6013	-0.0014
20	35	Biased-30krad	8.2069	8.3023	0.0954
30	50	Unbiased-50krad	8.2963	8.5012	0.2049
31	50	Unbiased-50krad	8.3094	8.3102	0.0008
32	50	Unbiased-50krad	8.1108	8.01	-0.1008
33	50	Unbiased-50krad	8.4015	8.4999	0.0984
34	50	Unbiased-50krad	7.9044	8.2075	0.3031
40	55	Biased-50krad	8.7014	8.596	-0.1054
41	55	Biased-50krad	8.3002	8.4959	0.1957
42	55	Biased-50krad	8.2963	8.4037	0.1074
43	55	Biased-50krad	8.4173	8.5934	0.1761
44	55	Biased-50krad	8.3068	8.4972	0.1904
45	100	Unbiased-100krad	8.508	8.596	0.088
46	100	Unbiased-100krad	8.3015	8.4972	0.1957
47	100	Unbiased-100krad	8.3055	7.8033	-0.5022
48	100	Unbiased-100krad	8.1122	8.3037	0.1915
49	100	Unbiased-100krad	8.391	8.4064	0.0154
50	105	Biased-100krad	8.2161	7.9982	-0.2179
51	105	Biased-100krad	8.0951	8.4946	0.3995
52	105	Biased-100krad	8.1976	7.9995	-0.1981
53	105	Biased-100krad	8.5948	8.197	-0.3978
54	105	Biased-100krad	8.0043	7.8006	-0.2037

Test Statistics (SIEMENS)

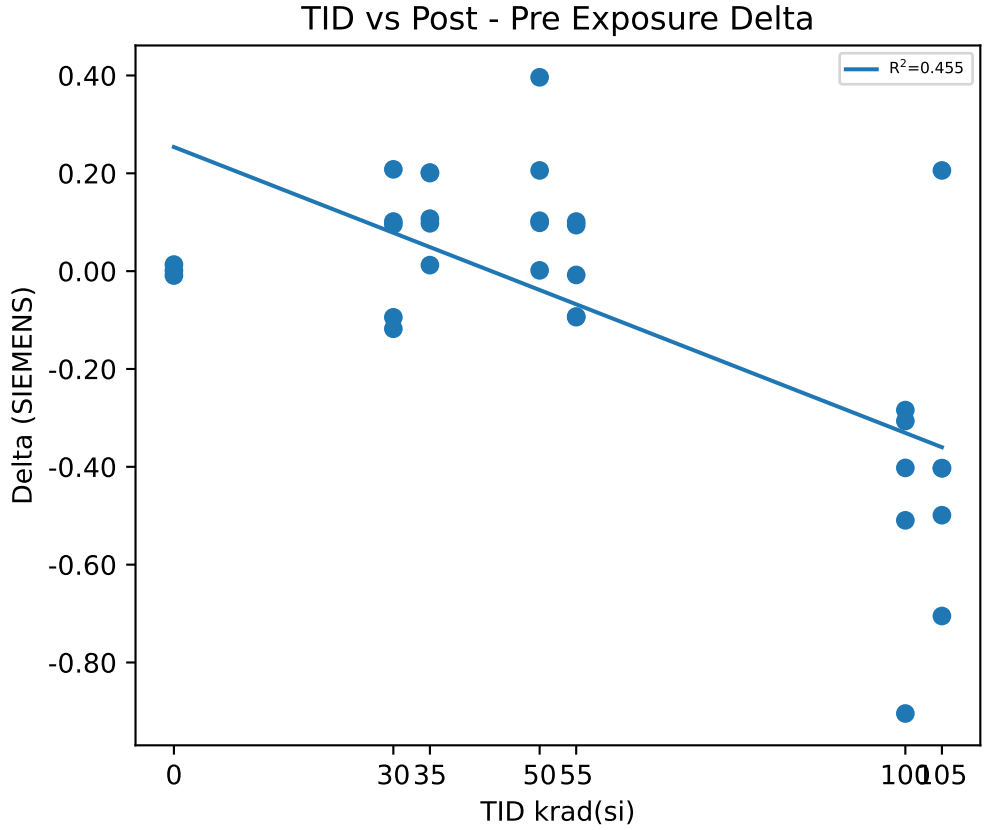
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.003	8.1393	8.3055	0.15344	8.0008	8.1729	8.4064	0.20967	-0.0022	0.033533	0.1009	0.058377
30	8.099	8.3652	8.5094	0.17144	8.2049	8.4045	8.6987	0.23205	-0.1084	0.0393	0.1959	0.1336
35	8.1108	8.3036	8.6027	0.18449	8.2944	8.3616	8.6013	0.13409	-0.0045	0.05794	0.1968	0.088148
50	7.9044	8.2045	8.4015	0.19817	8.01	8.3058	8.5012	0.20799	-0.1008	0.10128	0.3031	0.16001
55	8.2963	8.4044	8.7014	0.17353	8.4037	8.5172	8.596	0.080237	-0.1054	0.11284	0.1957	0.12703
100	8.1122	8.3236	8.508	0.14496	7.8033	8.3213	8.596	0.30914	-0.5022	-0.00232	0.1957	0.28945
105	8.0043	8.2216	8.5948	0.22534	7.8006	8.098	8.4946	0.2623	-0.3978	-0.1236	0.3995	0.30401

Device Test: 68.18 _EA_GMPS|GMPS/CH2/3/3///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

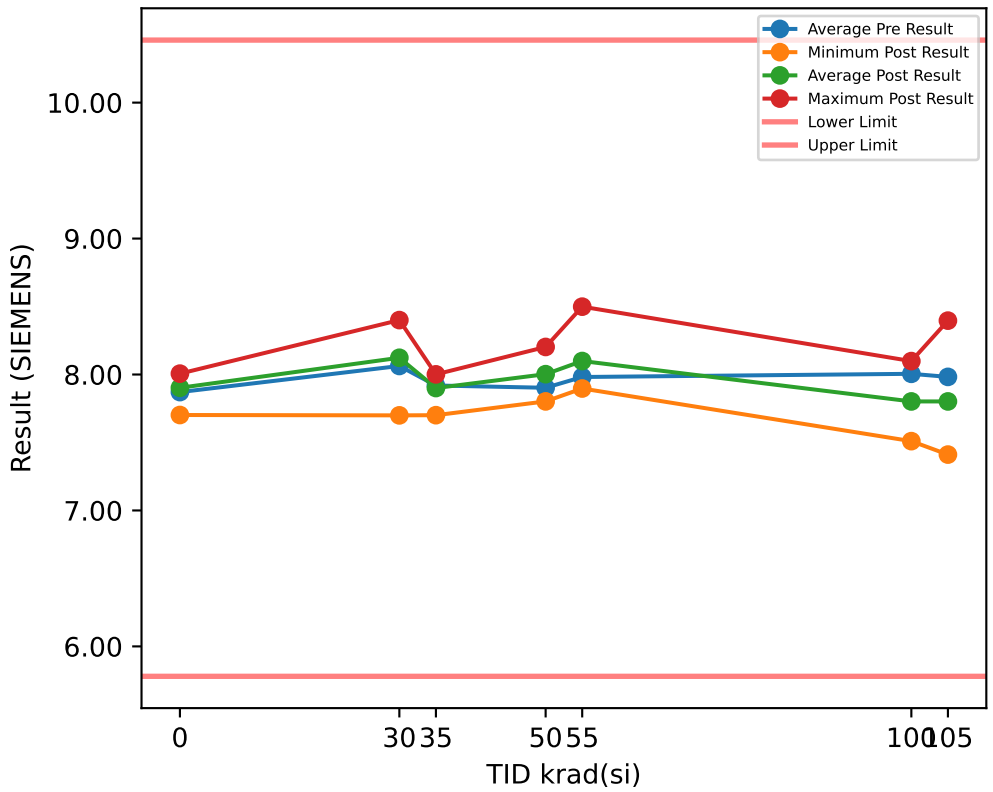
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	7.6979	7.6993	0.0014
2	0	CU2	7.8057	7.7967	-0.009
3	0	CU3	7.8938	7.9073	0.0135
11	30	Unbiased-30krad	8.2121	8.0943	-0.1178
12	30	Unbiased-30krad	7.6992	7.9073	0.2081
13	30	Unbiased-30krad	8.1043	8.1996	0.0953
14	30	Unbiased-30krad	7.9938	7.8994	-0.0944
15	30	Unbiased-30krad	7.7071	7.8085	0.1014
16	35	Biased-30krad	8.0004	8.0982	0.0978
17	35	Biased-30krad	7.9898	8.0021	0.0123
18	35	Biased-30krad	7.7018	7.9034	0.2016
19	35	Biased-30krad	8.1858	8.2931	0.1073
20	35	Biased-30krad	7.9004	8.1009	0.2005
30	50	Unbiased-50krad	7.8965	7.8981	0.0016
31	50	Unbiased-50krad	7.9057	8.0087	0.103
32	50	Unbiased-50krad	7.6032	7.9995	0.3963
33	50	Unbiased-50krad	8.103	8.3089	0.2059
34	50	Unbiased-50krad	7.7005	7.7993	0.0988
40	55	Biased-50krad	8.2016	8.1075	-0.0941
41	55	Biased-50krad	8.2963	8.2036	-0.0927
42	55	Biased-50krad	7.6992	7.8006	0.1014
43	55	Biased-50krad	7.7005	7.6927	-0.0078
44	55	Biased-50krad	8.0964	8.1904	0.094
45	100	Unbiased-100krad	8.0043	7.6979	-0.3064
46	100	Unbiased-100krad	8.2055	7.8033	-0.4022
47	100	Unbiased-100krad	7.9885	7.7045	-0.284
48	100	Unbiased-100krad	7.9004	6.9961	-0.9043
49	100	Unbiased-100krad	7.8018	7.2924	-0.5094
50	105	Biased-100krad	7.9977	8.2036	0.2059
51	105	Biased-100krad	7.6979	7.295	-0.4029
52	105	Biased-100krad	7.9044	7.5017	-0.4027
53	105	Biased-100krad	8.3029	7.5979	-0.705
54	105	Biased-100krad	7.7978	7.2989	-0.4989

Test Statistics (SIEMENS)

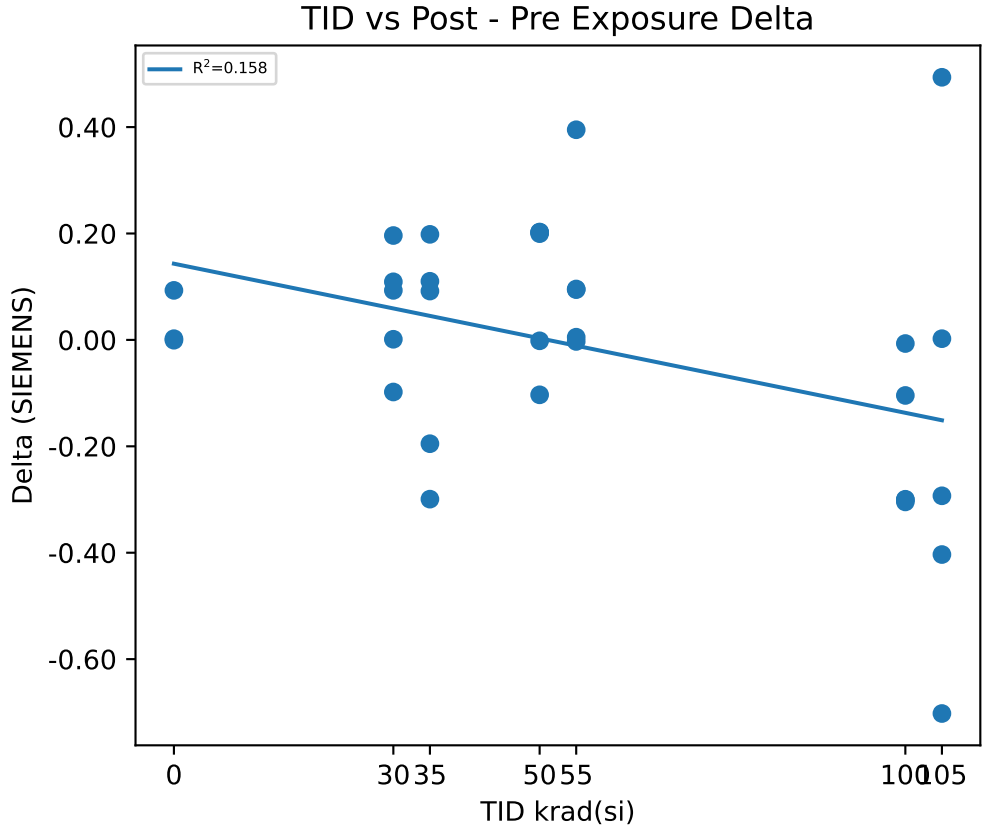
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.6979	7.7991	7.8938	0.098115	7.6993	7.8011	7.9073	0.10407	-0.009	0.0019667	0.0135	0.011261
30	7.6992	7.9433	8.2121	0.23243	7.8085	7.9818	8.1996	0.16005	-0.1178	0.03852	0.2081	0.13968
35	7.7018	7.9556	8.1858	0.17581	7.9034	8.0795	8.2931	0.14443	0.0123	0.1239	0.2016	0.079555
50	7.6032	7.8418	8.103	0.19506	7.7993	8.0029	8.3089	0.19113	0.0016	0.16112	0.3963	0.15002
55	7.6992	7.9988	8.2963	0.28191	7.6927	7.999	8.2036	0.23635	-0.0941	0.00016	0.1014	0.095691
100	7.8018	7.9801	8.2055	0.14967	6.9961	7.4988	7.8033	0.34278	-0.9043	-0.48126	-0.284	0.25273
105	7.6979	7.9401	8.3029	0.23191	7.295	7.5794	8.2036	0.37268	-0.705	-0.36072	0.2059	0.33993

Device Test: 68.19 _EA_GMPS|GMPS/CH3/3/3///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

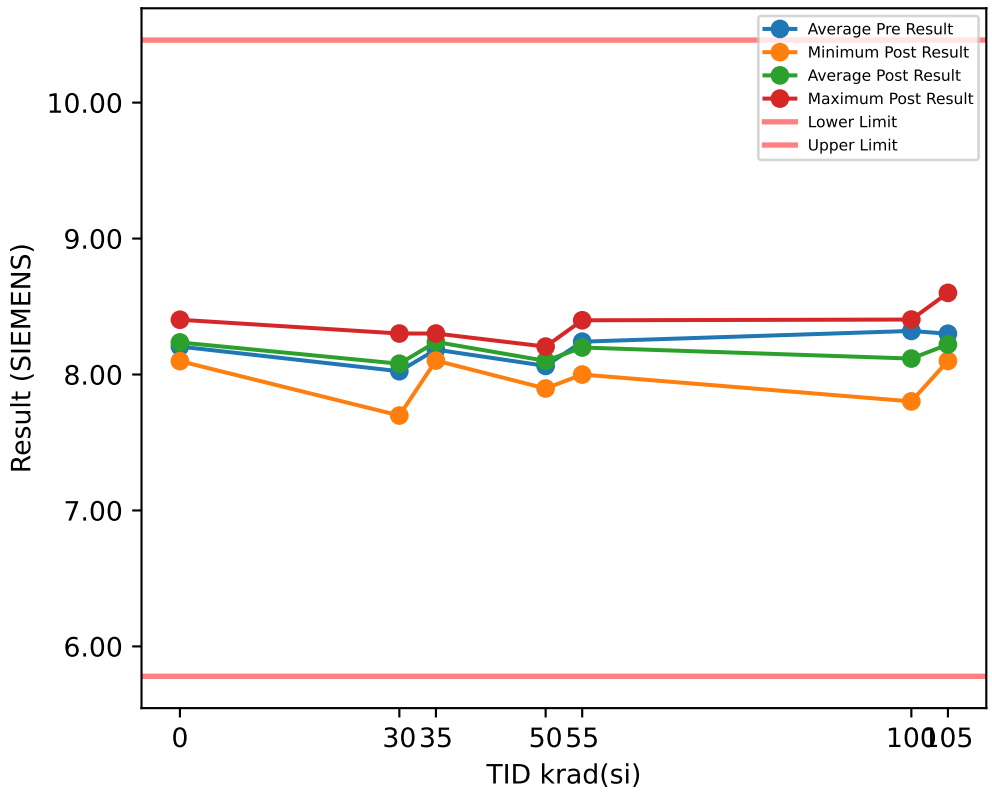
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	7.7027	7.7021	-0.0006
2	0	CU2	8.0041	8.0064	0.0023
3	0	CU3	7.9054	7.9985	0.0931
11	30	Unbiased-30krad	8.2028	8.312	0.1092
12	30	Unbiased-30krad	7.9014	7.9945	0.0931
13	30	Unbiased-30krad	8.2081	8.2093	0.0012
14	30	Unbiased-30krad	8.2041	8.4003	0.1962
15	30	Unbiased-30krad	7.7974	7.6995	-0.0979
16	35	Biased-30krad	8.0988	7.9037	-0.1951
17	35	Biased-30krad	7.8988	7.9906	0.0918
18	35	Biased-30krad	8.0001	7.7008	-0.2993
19	35	Biased-30krad	7.7961	7.9063	0.1102
20	35	Biased-30krad	7.8027	8.0011	0.1984
30	50	Unbiased-50krad	7.9027	7.901	-0.0017
31	50	Unbiased-50krad	7.9027	8.1052	0.2025
32	50	Unbiased-50krad	7.8014	8.0011	0.1997
33	50	Unbiased-50krad	7.9054	7.8022	-0.1032
34	50	Unbiased-50krad	8.0001	8.2027	0.2026
40	55	Biased-50krad	8.0988	8.1039	0.0051
41	55	Biased-50krad	8.1041	8.4991	0.395
42	55	Biased-50krad	7.8014	7.8971	0.0957
43	55	Biased-50krad	7.904	7.9985	0.0945
44	55	Biased-50krad	8.0001	7.9972	-0.0029
45	100	Unbiased-100krad	8.1054	8.0986	-0.0068
46	100	Unbiased-100krad	7.8093	7.5098	-0.2995
47	100	Unbiased-100krad	8.1054	7.8009	-0.3045
48	100	Unbiased-100krad	7.904	7.7996	-0.1044
49	100	Unbiased-100krad	8.1015	7.8009	-0.3006
50	105	Biased-100krad	8.0001	8.0024	0.0023
51	105	Biased-100krad	7.9027	8.3963	0.4936
52	105	Biased-100krad	8.3029	7.6007	-0.7022
53	105	Biased-100krad	8.0028	7.5994	-0.4034
54	105	Biased-100krad	7.704	7.411	-0.293

Test Statistics (SIEMENS)

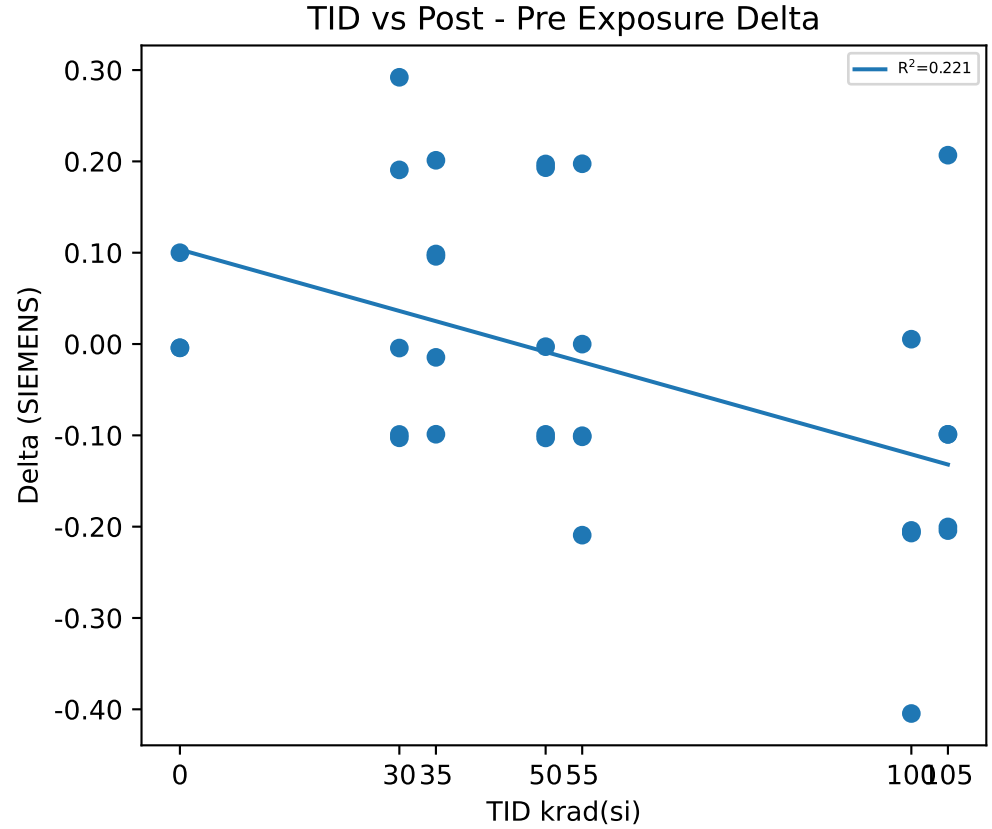
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.7027	7.8707	8.0041	0.15366	7.7021	7.9023	8.0064	0.17345	-0.0006	0.0316	0.0931	0.05328
30	7.7974	8.0628	8.2081	0.19822	7.6995	8.1231	8.4003	0.28104	-0.0979	0.06036	0.1962	0.11231
35	7.7961	7.9193	8.0988	0.13033	7.7008	7.9005	8.0011	0.12058	-0.2993	-0.0188	0.1984	0.21553
50	7.8014	7.9025	8.0001	0.070277	7.8022	8.0024	8.2027	0.15894	-0.1032	0.09998	0.2026	0.14371
55	7.8014	7.9817	8.1041	0.12998	7.8971	8.0992	8.4991	0.23523	-0.0029	0.11748	0.395	0.16213
100	7.8093	8.0051	8.1054	0.13962	7.5098	7.802	8.0986	0.20818	-0.3045	-0.20316	-0.0068	0.13907
105	7.704	7.9825	8.3029	0.2164	7.411	7.802	8.3963	0.39617	-0.7022	-0.18054	0.4936	0.45341

Device Test: 68.20 _EA_GMPS|GMPS/CH4/3/3///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



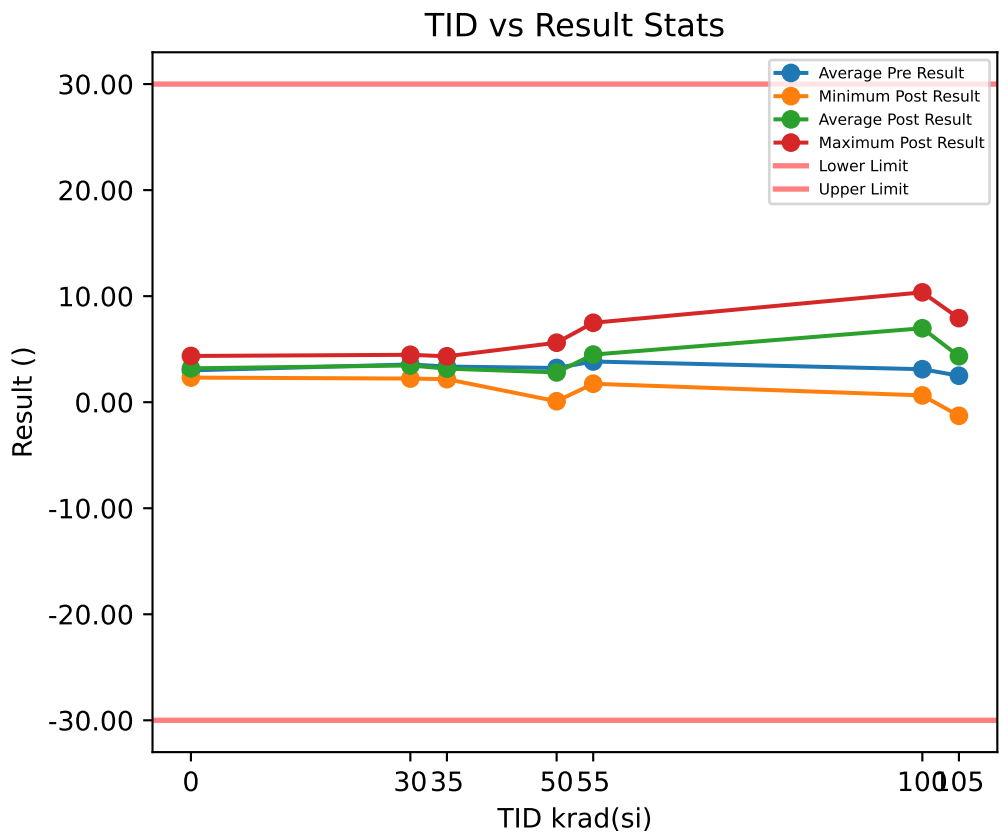
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

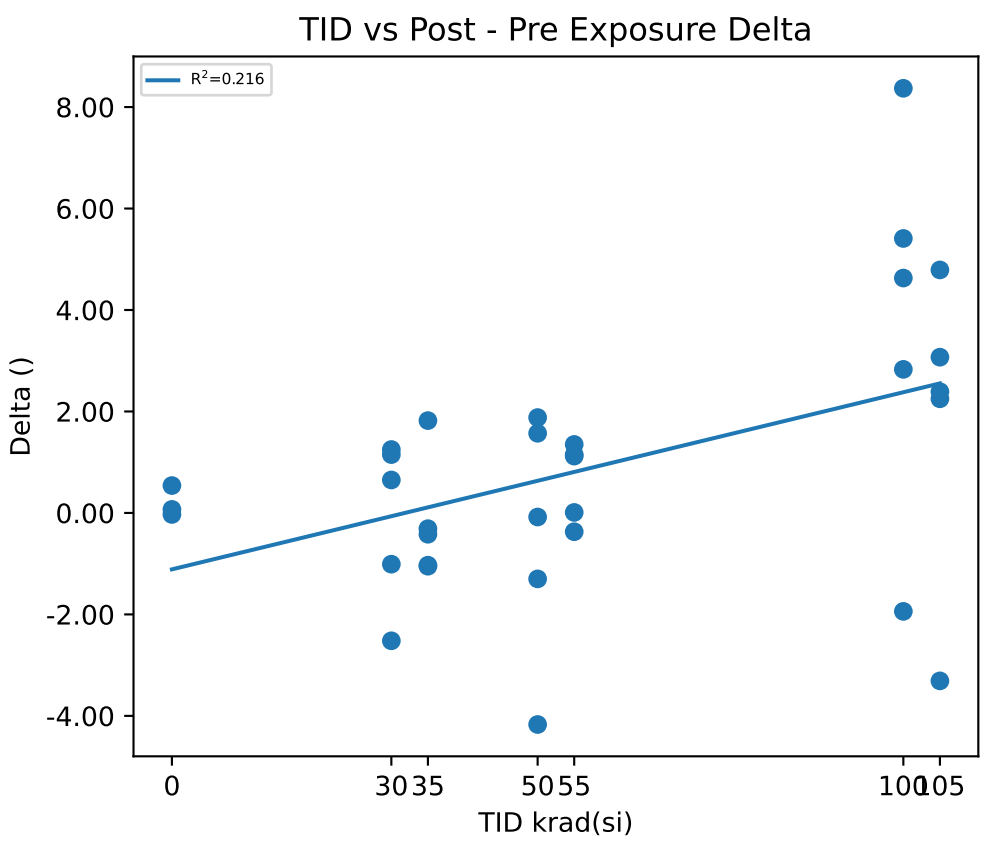
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.2107	8.2066	-0.0041
2	0	CU2	8.3029	8.4029	0.1
3	0	CU3	8.1028	8.0986	-0.0042
11	30	Unbiased-30krad	7.9014	8.1935	0.2921
12	30	Unbiased-30krad	8.0067	8.1974	0.1907
13	30	Unbiased-30krad	8.4042	8.3015	-0.1027
14	30	Unbiased-30krad	8.1054	8.0064	-0.099
15	30	Unbiased-30krad	7.7026	7.6982	-0.0044
16	35	Biased-30krad	8.1067	8.2053	0.0986
17	35	Biased-30krad	8.2055	8.3015	0.096
18	35	Biased-30krad	7.9014	8.1026	0.2012
19	35	Biased-30krad	8.3055	8.2909	-0.0146
20	35	Biased-30krad	8.3963	8.2975	-0.0988
30	50	Unbiased-50krad	8.3055	8.2027	-0.1028
31	50	Unbiased-50krad	8.3042	8.2053	-0.0989
32	50	Unbiased-50krad	7.9027	8.0999	0.1972
33	50	Unbiased-50krad	8.1002	8.0973	-0.0029
34	50	Unbiased-50krad	7.704	7.8971	0.1931
40	55	Biased-50krad	8.5029	8.2936	-0.2093
41	55	Biased-50krad	8.2002	8.0986	-0.1016
42	55	Biased-50krad	8.1002	7.9998	-0.1004
43	55	Biased-50krad	8.2028	8.2027	-0.0001
44	55	Biased-50krad	8.2015	8.3989	0.1974
45	100	Unbiased-100krad	8.1989	7.9919	-0.207
46	100	Unbiased-100krad	8.2963	8.0907	-0.2056
47	100	Unbiased-100krad	8.2068	7.8022	-0.4046
48	100	Unbiased-100krad	8.5016	8.2975	-0.2041
49	100	Unbiased-100krad	8.3989	8.4042	0.0053
50	105	Biased-100krad	8.3937	8.6005	0.2068
51	105	Biased-100krad	8.3002	8.0999	-0.2003
52	105	Biased-100krad	8.2989	8.2	-0.0989
53	105	Biased-100krad	8.3055	8.1012	-0.2043
54	105	Biased-100krad	8.2015	8.1026	-0.0989

Test Statistics (SIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.1028	8.2055	8.3029	0.10015	8.0986	8.236	8.4029	0.15427	-0.0042	0.030567	0.1	0.060131
30	7.7026	8.0241	8.4042	0.25971	7.6982	8.0794	8.3015	0.23818	-0.1027	0.05534	0.2921	0.17801
35	7.9014	8.1831	8.3963	0.19113	8.1026	8.2396	8.3015	0.086257	-0.0988	0.05648	0.2012	0.11559
50	7.704	8.0633	8.3055	0.26122	7.8971	8.1005	8.2053	0.12531	-0.1028	0.03714	0.1972	0.1497
55	8.1002	8.2415	8.5029	0.15256	7.9998	8.1987	8.3989	0.15707	-0.2093	-0.0428	0.1974	0.15331
100	8.1989	8.3205	8.5016	0.12966	7.8022	8.1173	8.4042	0.24005	-0.4046	-0.2032	0.0053	0.14496
105	8.2015	8.3	8.3937	0.068032	8.0999	8.2208	8.6005	0.2165	-0.2043	-0.07912	0.2068	0.16799

Device Test: 68.21 _EA_GMPS|GMPS_Matching/CH1/3/3///90.9/634//0///@PS_GM_MATCH





Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

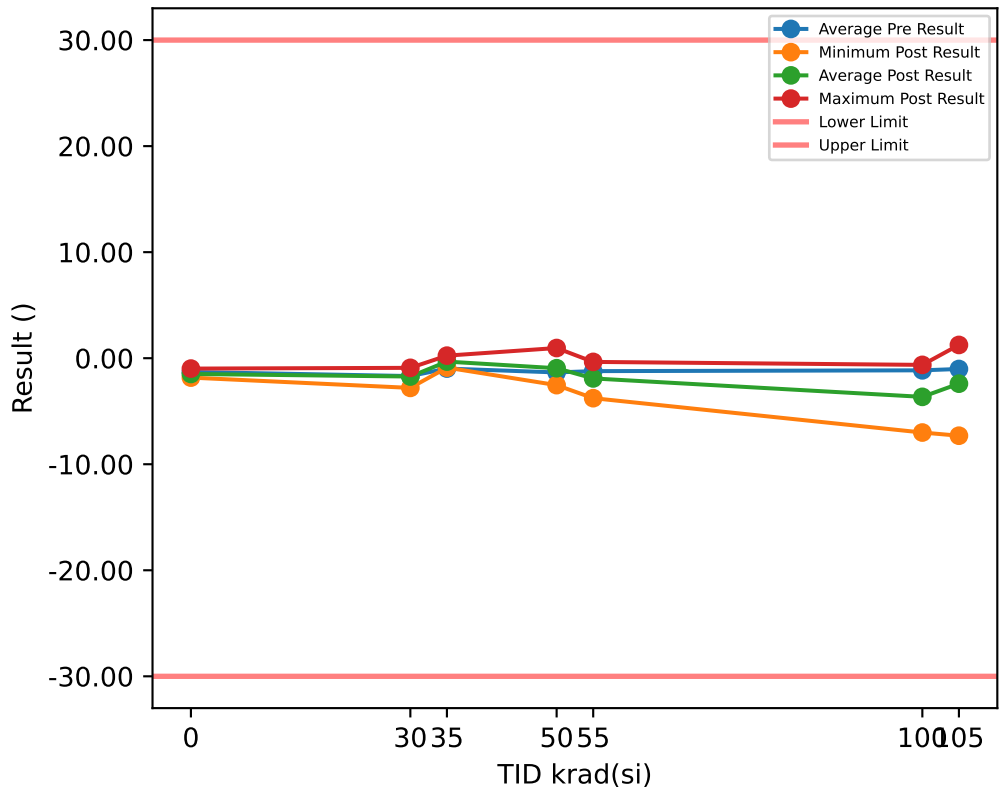
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.93	2.9	-0.03
2	0	CU2	2.25	2.32	0.07
3	0	CU3	3.82	4.36	0.54
11	30	Unbiased-30krad	2.72	3.97	1.25
12	30	Unbiased-30krad	5.05	2.53	-2.52
13	30	Unbiased-30krad	3.32	4.47	1.15
14	30	Unbiased-30krad	3.24	2.23	-1.01
15	30	Unbiased-30krad	3.47	4.12	0.65
16	35	Biased-30krad	0.72	2.54	1.82
17	35	Biased-30krad	3.24	2.82	-0.42
18	35	Biased-30krad	4.64	4.33	-0.31
19	35	Biased-30krad	5.01	3.96	-1.05
20	35	Biased-30krad	3.2	2.17	-1.03
30	50	Unbiased-50krad	3.73	5.61	1.88
31	50	Unbiased-50krad	3.79	2.49	-1.3
32	50	Unbiased-50krad	4.26	0.09	-4.17
33	50	Unbiased-50krad	3.36	3.28	-0.08
34	50	Unbiased-50krad	1	2.57	1.57
40	55	Biased-50krad	4.83	4.46	-0.37
41	55	Biased-50krad	0.62	1.74	1.12
42	55	Biased-50krad	5.36	5.37	0.01
43	55	Biased-50krad	6.14	7.49	1.35
44	55	Biased-50krad	2.24	3.39	1.15
45	100	Unbiased-100krad	4.32	7.15	2.83
46	100	Unbiased-100krad	2.1	7.51	5.41
47	100	Unbiased-100krad	2.58	0.64	-1.94
48	100	Unbiased-100krad	1.99	10.36	8.37
49	100	Unbiased-100krad	4.57	9.2	4.63
50	105	Biased-100krad	2.03	-1.28	-3.31
51	105	Biased-100krad	3.14	7.93	4.79
52	105	Biased-100krad	1.49	4.56	3.07
53	105	Biased-100krad	3.54	5.79	2.25
54	105	Biased-100krad	2.28	4.67	2.39

Test Statistics ()

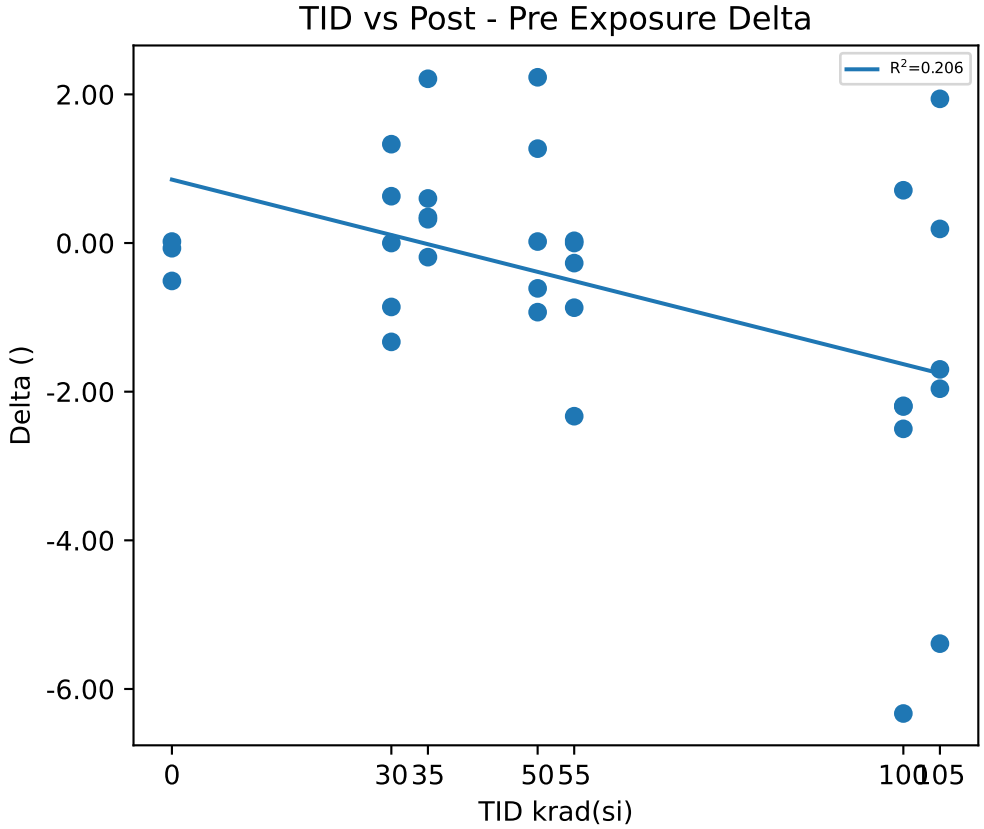
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.25	3	3.82	0.78734	2.32	3.1933	4.36	1.0512	-0.03	0.19333	0.54	0.30436
30	2.72	3.56	5.05	0.87946	2.23	3.464	4.47	1.0116	-2.52	-0.096	1.25	1.6303
35	0.72	3.362	5.01	1.686	2.17	3.164	4.33	0.93393	-1.05	-0.198	1.82	1.1782
50	1	3.228	4.26	1.2859	0.09	2.808	5.61	1.9761	-4.17	-0.42	1.88	2.4598
55	0.62	3.838	6.14	2.3189	1.74	4.49	7.49	2.1534	-0.37	0.652	1.35	0.77635
100	1.99	3.112	4.57	1.2401	0.64	6.972	10.36	3.7702	-1.94	3.86	8.37	3.8091
105	1.49	2.496	3.54	0.83374	-1.28	4.334	7.93	3.418	-3.31	1.838	4.79	3.0499

Device Test: 68.22 _EA_GMPS|GMPS_Matching/CH2/3/3///90.9/634//0///@PS_GM_MATCH

TID vs Result Stats



TID vs Post - Pre Exposure Delta



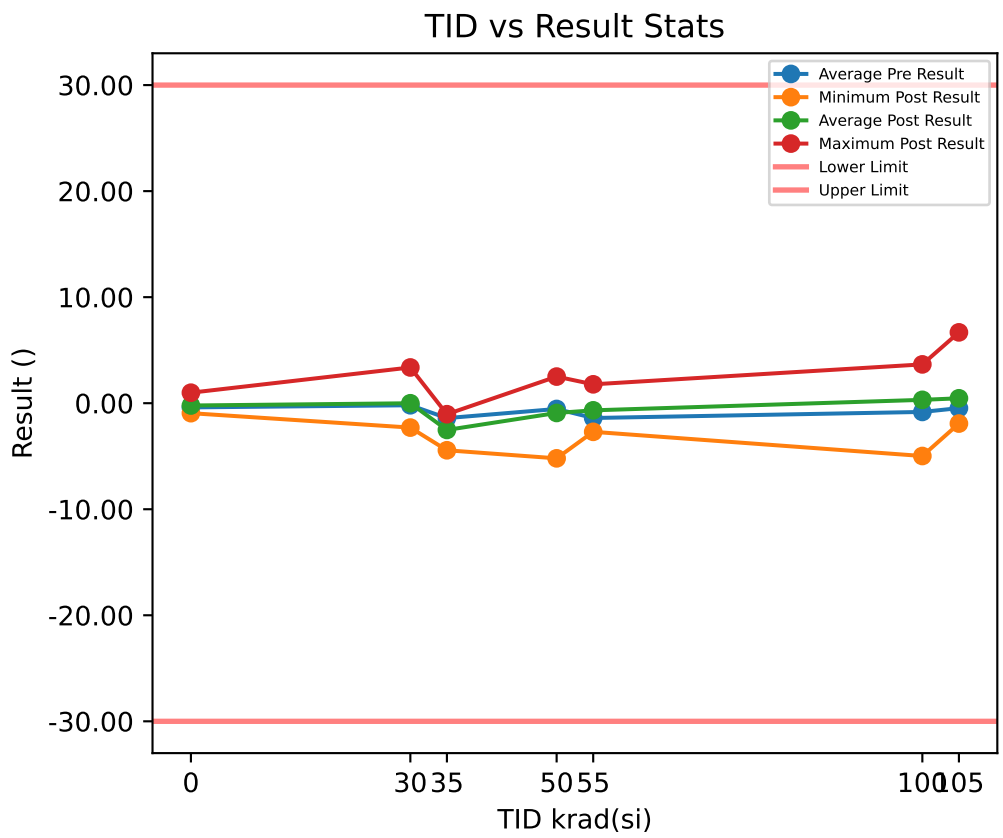
Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

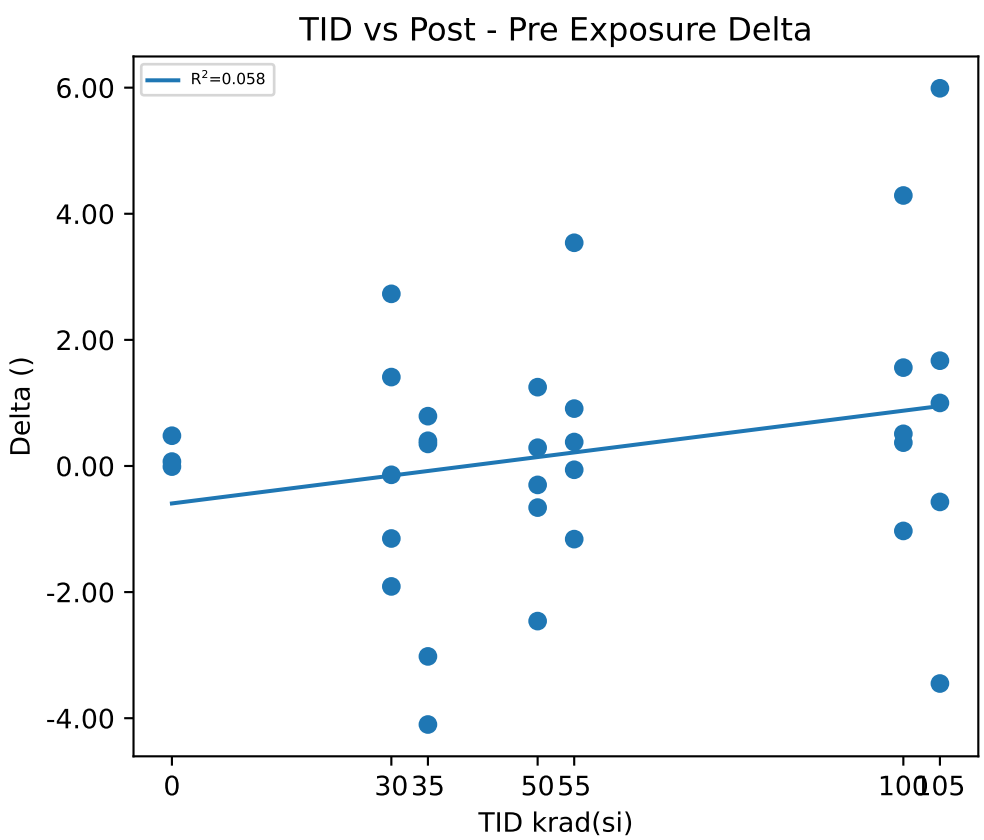
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-1	-0.98	0.02
2	0	CU2	-1.58	-1.65	-0.07
3	0	CU3	-1.32	-1.83	-0.51
11	30	Unbiased-30krad	-0.87	-2.2	-1.33
12	30	Unbiased-30krad	-2.54	-1.21	1.33
13	30	Unbiased-30krad	-1.53	-1.53	0
14	30	Unbiased-30krad	-1.94	-2.8	-0.86
15	30	Unbiased-30krad	-1.54	-0.91	0.63
16	35	Biased-30krad	-0.65	-0.05	0.6
17	35	Biased-30krad	-0.7	-0.89	-0.19
18	35	Biased-30krad	-2.8	-0.59	2.21
19	35	Biased-30krad	-0.08	0.24	0.32
20	35	Biased-30krad	-0.66	-0.31	0.35
30	50	Unbiased-50krad	-1.27	-1.88	-0.61
31	50	Unbiased-50krad	-1.25	-1.23	0.02
32	50	Unbiased-50krad	-2.27	-0.04	2.23
33	50	Unbiased-50krad	-0.31	0.96	1.27
34	50	Unbiased-50krad	-1.61	-2.54	-0.93
40	55	Biased-50krad	-1.2	-1.47	-0.27
41	55	Biased-50krad	0.57	-1.76	-2.33
42	55	Biased-50krad	-2.22	-2.19	0.03
43	55	Biased-50krad	-2.9	-3.77	-0.87
44	55	Biased-50krad	-0.35	-0.35	0
45	100	Unbiased-100krad	-1.85	-4.05	-2.2
46	100	Unbiased-100krad	0.92	-1.27	-2.19
47	100	Unbiased-100krad	-1.34	-0.63	0.71
48	100	Unbiased-100krad	-0.68	-7.01	-6.33
49	100	Unbiased-100krad	-2.77	-5.27	-2.5
50	105	Biased-100krad	-0.69	1.25	1.94
51	105	Biased-100krad	-1.92	-7.31	-5.39
52	105	Biased-100krad	-2.14	-1.95	0.19
53	105	Biased-100krad	0.02	-1.94	-1.96
54	105	Biased-100krad	-0.36	-2.06	-1.7

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-1.58	-1.3	-1	0.29052	-1.83	-1.4867	-0.98	0.44792	-0.51	-0.18667	0.02	0.28361
30	-2.54	-1.684	-0.87	0.61346	-2.8	-1.73	-0.91	0.76626	-1.33	-0.046	1.33	1.0798
35	-2.8	-0.978	-0.08	1.0502	-0.89	-0.32	0.24	0.44283	-0.19	0.658	2.21	0.91382
50	-2.27	-1.342	-0.31	0.70917	-2.54	-0.946	0.96	1.4096	-0.93	0.396	2.23	1.3266
55	-2.9	-1.22	0.57	1.395	-3.77	-1.908	-0.35	1.2438	-2.33	-0.688	0.03	0.98652
100	-2.77	-1.144	0.92	1.3835	-7.01	-3.646	-0.63	2.686	-6.33	-2.502	0.71	2.5079
105	-2.14	-1.018	0.02	0.96053	-7.31	-2.402	1.25	3.0806	-5.39	-1.384	1.94	2.7389

Device Test: 68.23 _EA_GMPS|GMPS_Matching/CH3/3/3///90.9/634//0///@PS_GM_MATCH





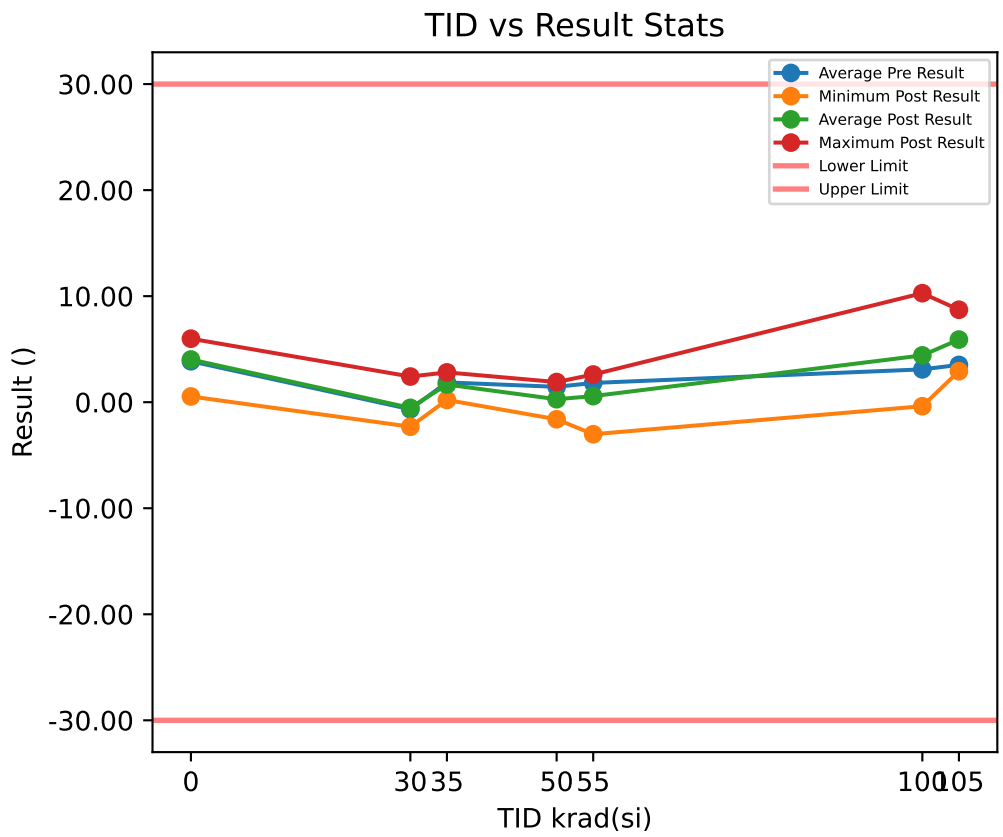
Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

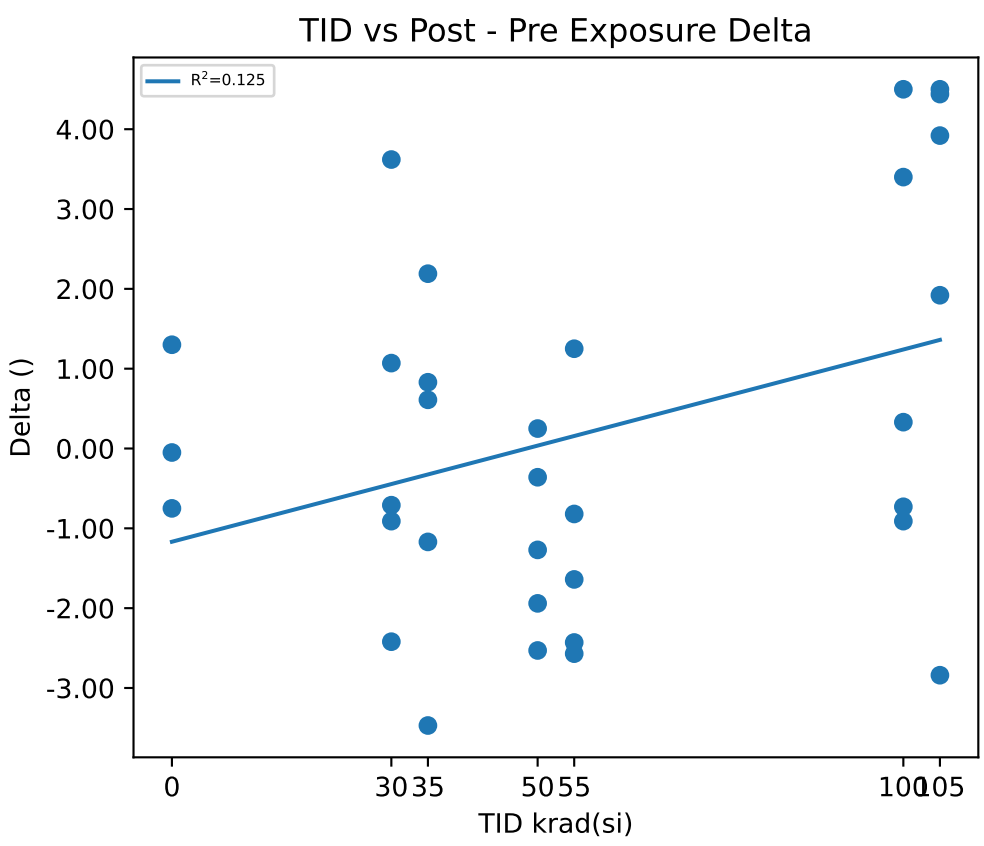
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.93	-0.94	-0.01
2	0	CU2	0.92	0.99	0.07
3	0	CU3	-1.18	-0.7	0.48
11	30	Unbiased-30krad	-0.98	0.43	1.41
12	30	Unbiased-30krad	0.02	-0.12	-0.14
13	30	Unbiased-30krad	-0.26	-1.41	-1.15
14	30	Unbiased-30krad	0.64	3.37	2.73
15	30	Unbiased-30krad	-0.39	-2.3	-1.91
16	35	Biased-30krad	0.57	-2.45	-3.02
17	35	Biased-30krad	-1.83	-1.04	0.79
18	35	Biased-30krad	0.96	-3.14	-4.1
19	35	Biased-30krad	-4.84	-4.44	0.4
20	35	Biased-30krad	-1.89	-1.54	0.35
30	50	Unbiased-50krad	-1.19	-1.85	-0.66
31	50	Unbiased-50krad	-1.29	-0.04	1.25
32	50	Unbiased-50krad	0.28	-0.02	-0.3
33	50	Unbiased-50krad	-2.74	-5.2	-2.46
34	50	Unbiased-50krad	2.22	2.51	0.29
40	55	Biased-50krad	-2.43	-1.52	0.91
41	55	Biased-50krad	-1.76	1.78	3.54
42	55	Biased-50krad	-0.92	-0.98	-0.06
43	55	Biased-50krad	-0.33	0.05	0.38
44	55	Biased-50krad	-1.54	-2.7	-1.16
45	100	Unbiased-100krad	-0.61	0.95	1.56
46	100	Unbiased-100krad	-3.95	-4.98	-1.03
47	100	Unbiased-100krad	0.1	0.61	0.51
48	100	Unbiased-100krad	-0.63	3.66	4.29
49	100	Unbiased-100krad	0.97	1.34	0.37
50	105	Biased-100krad	-0.66	-1.23	-0.57
51	105	Biased-100krad	0.69	6.68	5.99
52	105	Biased-100krad	2.79	-0.66	-3.45
53	105	Biased-100krad	-3.59	-1.92	1.67
54	105	Biased-100krad	-1.56	-0.56	1

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-1.18	-0.39667	0.92	1.1471	-0.94	-0.21667	0.99	1.0519	-0.01	0.18	0.48	0.26287
30	-0.98	-0.194	0.64	0.59201	-2.3	-0.006	3.37	2.1699	-1.91	0.188	2.73	1.8878
35	-4.84	-1.406	0.96	2.3296	-4.44	-2.522	-1.04	1.3441	-4.1	-1.116	0.79	2.2699
50	-2.74	-0.544	2.22	1.8785	-5.2	-0.92	2.51	2.8519	-2.46	-0.376	1.25	1.3709
55	-2.43	-1.396	-0.33	0.80395	-2.7	-0.674	1.78	1.6927	-1.16	0.722	3.54	1.7498
100	-3.95	-0.824	0.97	1.866	-4.98	0.316	3.66	3.1924	-1.03	1.14	4.29	1.9873
105	-3.59	-0.466	2.79	2.3944	-1.92	0.462	6.68	3.5179	-3.45	0.928	5.99	3.4493

Device Test: 68.24 _EA_GMPS|GMPS_Matching/CH4/3/3///90.9/634//0///@PS_GM_MATCH





Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

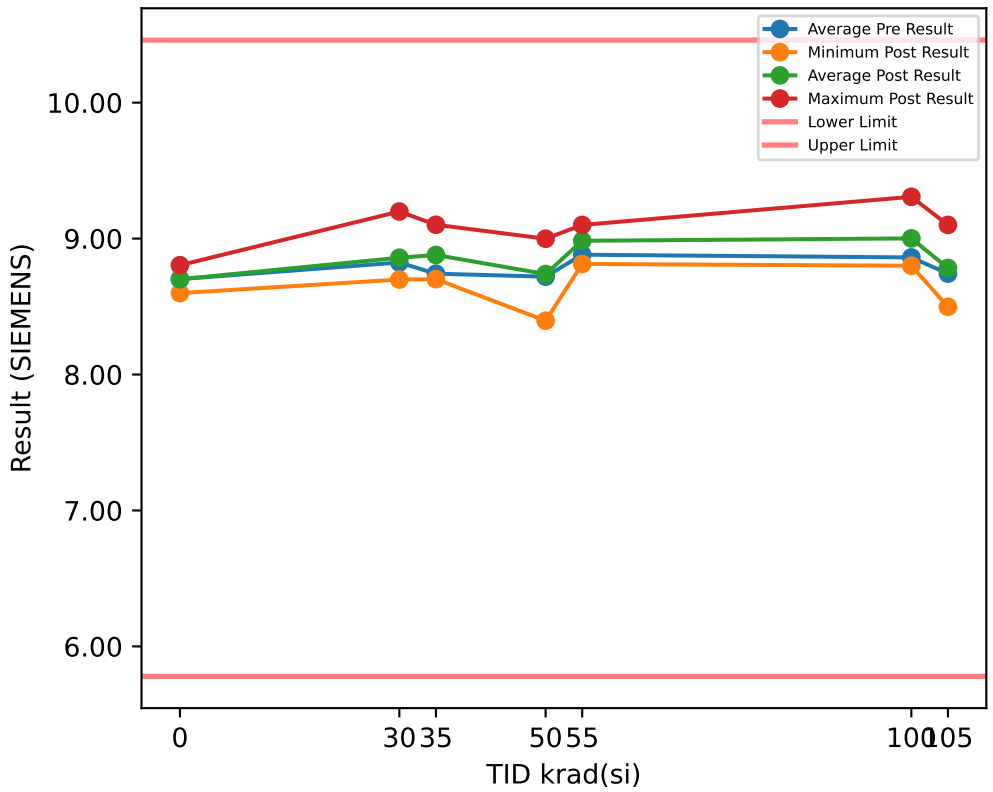
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.6	5.55	-0.05
2	0	CU2	4.69	5.99	1.3
3	0	CU3	1.29	0.54	-0.75
11	30	Unbiased-30krad	-4.62	-1	3.62
12	30	Unbiased-30krad	1.35	2.42	1.07
13	30	Unbiased-30krad	2.12	-0.3	-2.42
14	30	Unbiased-30krad	-0.57	-1.48	-0.91
15	30	Unbiased-30krad	-1.6	-2.31	-0.71
16	35	Biased-30krad	0.67	1.28	0.61
17	35	Biased-30krad	1.98	2.81	0.83
18	35	Biased-30krad	-0.28	1.91	2.19
19	35	Biased-30krad	1.38	0.21	-1.17
20	35	Biased-30krad	5.58	2.11	-3.47
30	50	Unbiased-50krad	3.84	1.9	-1.94
31	50	Unbiased-50krad	3.73	1.2	-2.53
32	50	Unbiased-50krad	1.58	1.22	-0.36
33	50	Unbiased-50krad	-0.34	-1.61	-1.27
34	50	Unbiased-50krad	-1.56	-1.31	0.25
40	55	Biased-50krad	2.43	0.79	-1.64
41	55	Biased-50krad	-0.59	-3.02	-2.43
42	55	Biased-50krad	2.87	0.3	-2.57
43	55	Biased-50krad	3.43	2.61	-0.82
44	55	Biased-50krad	0.94	2.19	1.25
45	100	Unbiased-100krad	0.53	-0.38	-0.91
46	100	Unbiased-100krad	2.04	2.37	0.33
47	100	Unbiased-100krad	1.36	0.63	-0.73
48	100	Unbiased-100krad	6.88	10.28	3.4
49	100	Unbiased-100krad	4.67	9.17	4.5
50	105	Biased-100krad	4.23	6.15	1.92
51	105	Biased-100krad	5.76	2.92	-2.84
52	105	Biased-100krad	2.74	7.18	4.44
53	105	Biased-100krad	0.06	4.56	4.5
54	105	Biased-100krad	4.8	8.72	3.92

Test Statistics ()

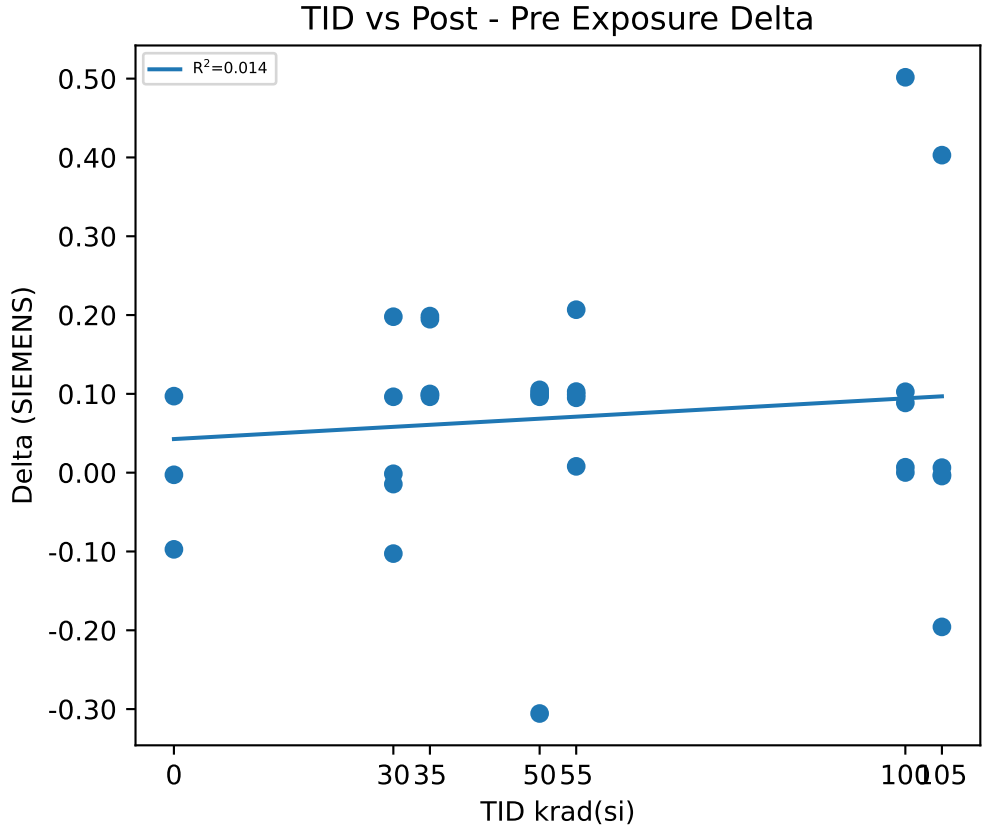
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.29	3.86	5.6	2.2717	0.54	4.0267	5.99	3.0275	-0.75	0.16667	1.3	1.042
30	-4.62	-0.664	2.12	2.6618	-2.31	-0.534	2.42	1.806	-2.42	0.13	3.62	2.3105
35	-0.28	1.866	5.58	2.2405	0.21	1.664	2.81	0.97907	-3.47	-0.202	2.19	2.1831
50	-1.56	1.45	3.84	2.4079	-1.61	0.28	1.9	1.6167	-2.53	-1.17	0.25	1.1319
55	-0.59	1.816	3.43	1.6316	-3.02	0.574	2.61	2.2246	-2.57	-1.242	1.25	1.559
100	0.53	3.096	6.88	2.6225	-0.38	4.414	10.28	4.9626	-0.91	1.318	4.5	2.4796
105	0.06	3.518	5.76	2.2215	2.92	5.906	8.72	2.2544	-2.84	2.388	4.5	3.1052

Device Test: 69.17 _EA_GMPS|GMPS/CH1/7/7///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

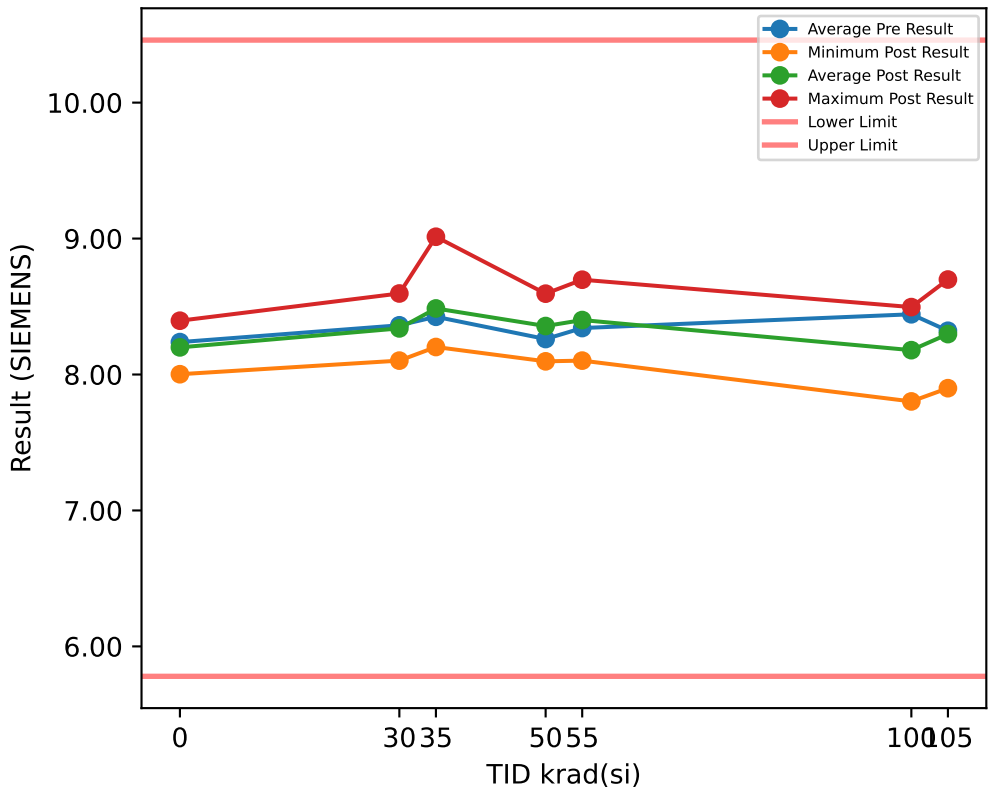
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.5015	8.5986	0.0971
2	0	CU2	8.7027	8.7	-0.0027
3	0	CU3	8.9013	8.804	-0.0973
11	30	Unbiased-30krad	9.0012	9.1991	0.1979
12	30	Unbiased-30krad	8.7001	8.6987	-0.0014
13	30	Unbiased-30krad	8.9013	8.9976	0.0963
14	30	Unbiased-30krad	8.804	8.7013	-0.1027
15	30	Unbiased-30krad	8.7132	8.6987	-0.0145
16	35	Biased-30krad	8.6014	8.7013	0.0999
17	35	Biased-30krad	8.9013	8.9976	0.0963
18	35	Biased-30krad	8.6014	8.7961	0.1947
19	35	Biased-30krad	9.0026	9.1016	0.099
20	35	Biased-30krad	8.6014	8.8001	0.1987
30	50	Unbiased-50krad	8.8	8.8988	0.0988
31	50	Unbiased-50krad	8.6974	8.7988	0.1014
32	50	Unbiased-50krad	8.7014	8.3958	-0.3056
33	50	Unbiased-50krad	8.9026	8.9989	0.0963
34	50	Unbiased-50krad	8.4975	8.6026	0.1051
40	55	Biased-50krad	9.0012	9.1003	0.0991
41	55	Biased-50krad	8.9052	9.0002	0.095
42	55	Biased-50krad	8.7934	9.0002	0.2068
43	55	Biased-50krad	8.8053	8.8133	0.008
44	55	Biased-50krad	8.9013	9.0042	0.1029
45	100	Unbiased-100krad	8.9933	9.0002	0.0069
46	100	Unbiased-100krad	8.8053	9.307	0.5017
47	100	Unbiased-100krad	8.9039	8.9041	0.0002
48	100	Unbiased-100krad	8.6974	8.8001	0.1027
49	100	Unbiased-100krad	8.9065	8.995	0.0885
50	105	Biased-100krad	8.5028	8.4985	-0.0043
51	105	Biased-100krad	8.6974	9.1003	0.4029
52	105	Biased-100krad	8.804	8.8014	-0.0026
53	105	Biased-100krad	9.1051	8.9094	-0.1957
54	105	Biased-100krad	8.6014	8.6078	0.0064

Test Statistics (SIEMENS)

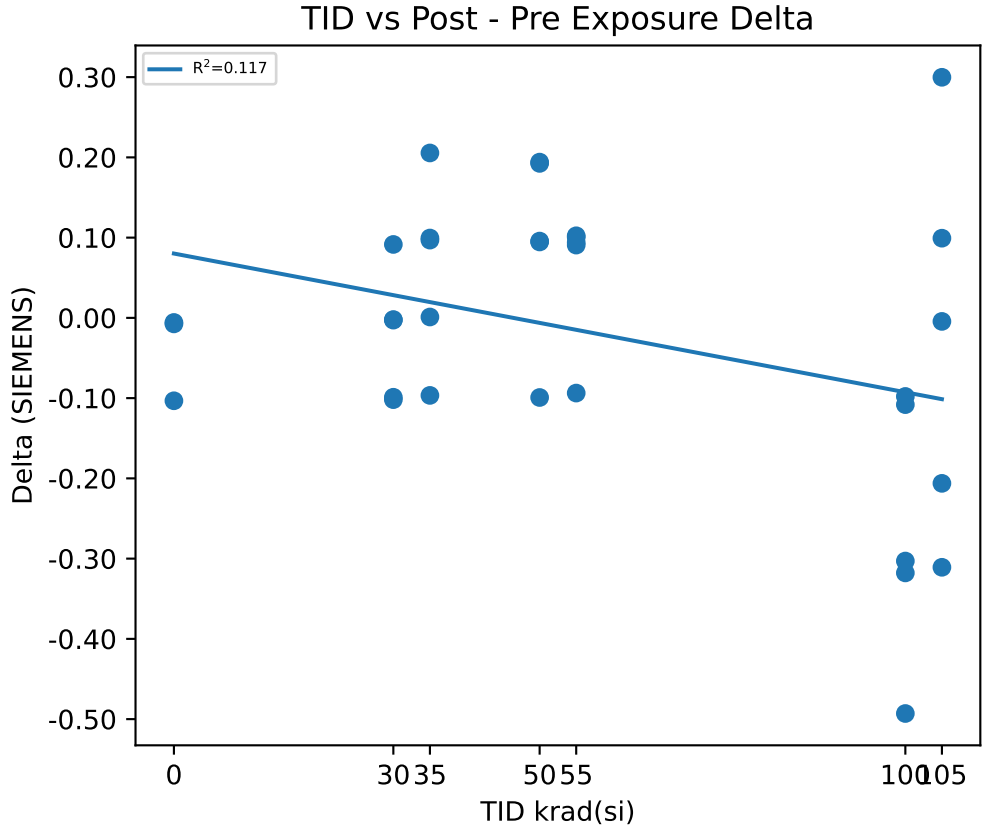
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.5015	8.7018	8.9013	0.1999	8.5986	8.7009	8.804	0.1027	-0.0973	-0.00096667	0.0971	0.097212
30	8.7001	8.824	9.0012	0.12787	8.6987	8.8591	9.1991	0.22975	-0.1027	0.03512	0.1979	0.11514
35	8.6014	8.7416	9.0026	0.19532	8.7013	8.8793	9.1016	0.16454	0.0963	0.13772	0.1987	0.053876
50	8.4975	8.7198	8.9026	0.15009	8.3958	8.739	8.9989	0.24138	-0.3056	0.0192	0.1051	0.1816
55	8.7934	8.8813	9.0012	0.084926	8.8133	8.9836	9.1003	0.1044	0.008	0.10236	0.2068	0.070492
100	8.6974	8.8613	8.9933	0.11323	8.8001	9.0013	9.307	0.18936	0.0002	0.14	0.5017	0.20744
105	8.5028	8.7421	9.1051	0.23166	8.4985	8.7835	9.1003	0.23908	-0.1957	0.04134	0.4029	0.21917

Device Test: 69.18 _EA_GMPS|GMPS/CH2/7/7///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

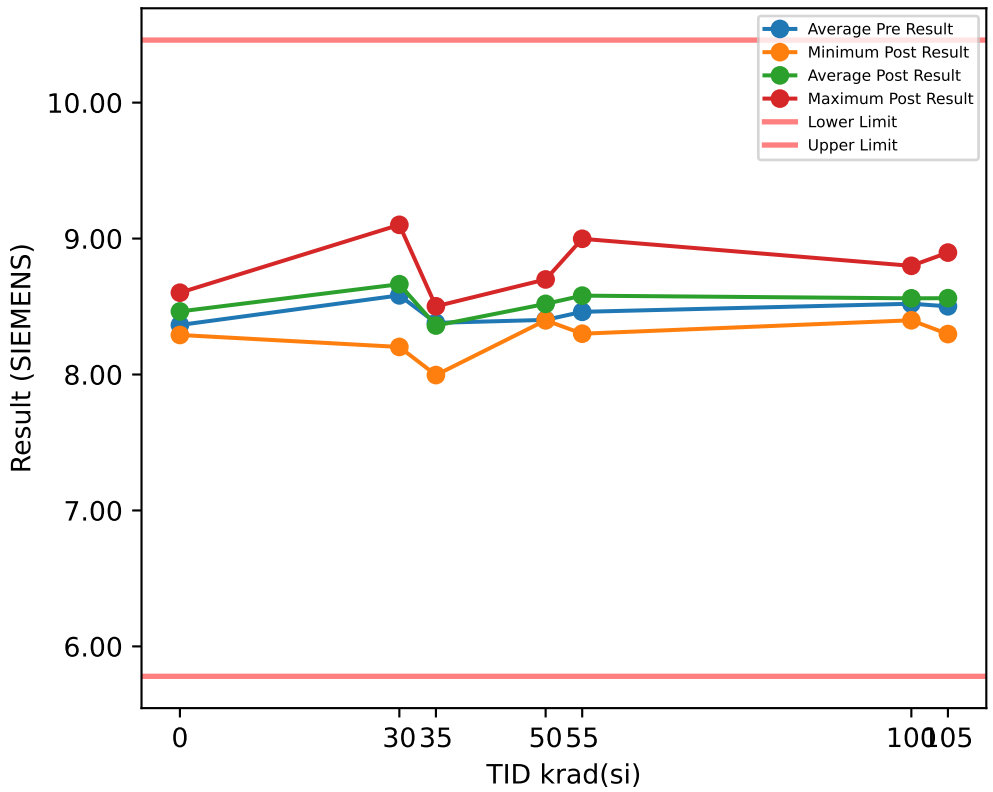
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.0096	8.0021	-0.0075
2	0	CU2	8.3042	8.2009	-0.1033
3	0	CU3	8.4015	8.3958	-0.0057
11	30	Unbiased-30krad	8.604	8.5051	-0.0989
12	30	Unbiased-30krad	8.2029	8.2944	0.0915
13	30	Unbiased-30krad	8.5988	8.596	-0.0028
14	30	Unbiased-30krad	8.3002	8.1983	-0.1019
15	30	Unbiased-30krad	8.1043	8.1022	-0.0021
16	35	Biased-30krad	8.4988	8.4999	0.0011
17	35	Biased-30krad	8.2989	8.2023	-0.0966
18	35	Biased-30krad	8.2055	8.305	0.0995
19	35	Biased-30krad	8.8079	9.0134	0.2055
20	35	Biased-30krad	8.3121	8.409	0.0969
30	50	Unbiased-50krad	8.3976	8.2984	-0.0992
31	50	Unbiased-50krad	8.4028	8.4985	0.0957
32	50	Unbiased-50krad	8.1003	8.2944	0.1941
33	50	Unbiased-50krad	8.5001	8.5947	0.0946
34	50	Unbiased-50krad	7.9044	8.0969	0.1925
40	55	Biased-50krad	8.5962	8.5025	-0.0937
41	55	Biased-50krad	8.6067	8.6974	0.0907
42	55	Biased-50krad	8.1069	8.2009	0.094
43	55	Biased-50krad	8.0017	8.1022	0.1005
44	55	Biased-50krad	8.3976	8.4999	0.1023
45	100	Unbiased-100krad	8.6014	8.2984	-0.303
46	100	Unbiased-100krad	8.604	8.4959	-0.1081
47	100	Unbiased-100krad	8.3976	8.2997	-0.0979
48	100	Unbiased-100krad	8.3173	7.9995	-0.3178
49	100	Unbiased-100krad	8.295	7.802	-0.493
50	105	Biased-100krad	8.3989	8.6987	0.2998
51	105	Biased-100krad	8.1056	7.8994	-0.2062
52	105	Biased-100krad	8.3015	8.2971	-0.0044
53	105	Biased-100krad	8.7053	8.3945	-0.3108
54	105	Biased-100krad	8.0977	8.197	0.0993

Test Statistics (SIEMENS)

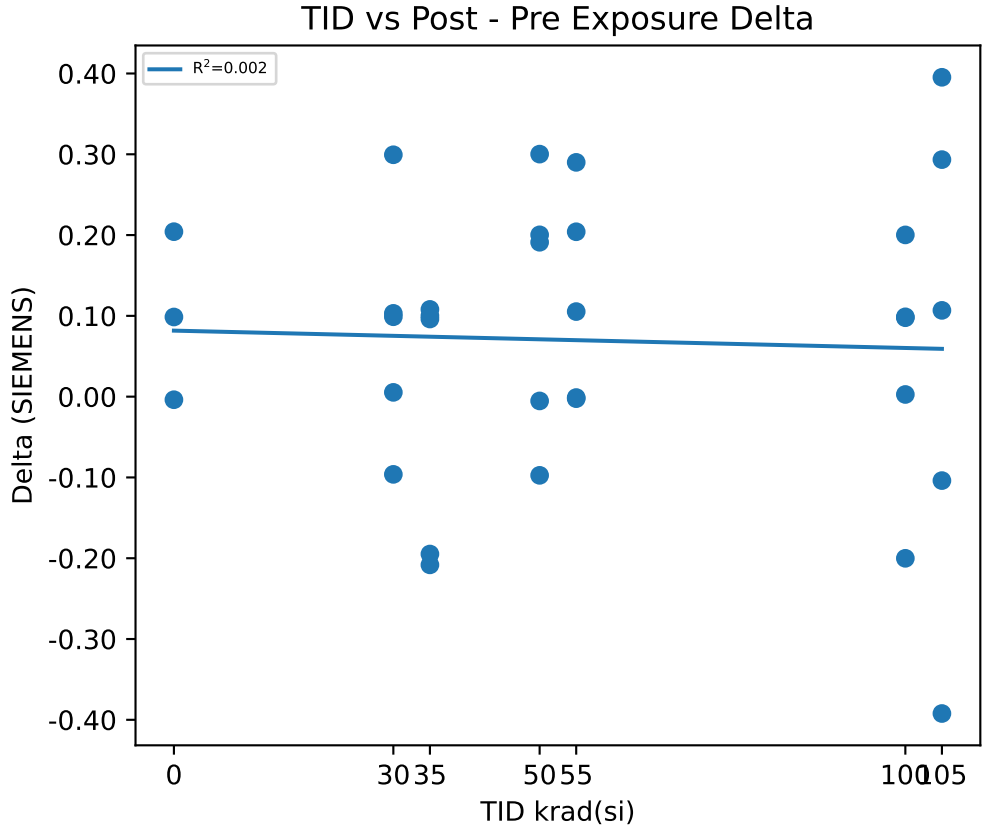
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0096	8.2384	8.4015	0.20406	8.0021	8.1996	8.3958	0.19685	-0.1033	-0.038833	-0.0057	0.055837
30	8.1043	8.362	8.604	0.22923	8.1022	8.3392	8.596	0.20706	-0.1019	-0.02284	0.0915	0.080531
35	8.2055	8.4246	8.8079	0.23921	8.2023	8.4859	9.0134	0.31525	-0.0966	0.06128	0.2055	0.1141
50	7.9044	8.261	8.5001	0.24946	8.0969	8.3566	8.5947	0.19463	-0.0992	0.09554	0.1941	0.11942
55	8.0017	8.3418	8.6067	0.27787	8.1022	8.4006	8.6974	0.24355	-0.0937	0.05876	0.1023	0.085358
100	8.295	8.4431	8.604	0.15065	7.802	8.1791	8.4959	0.2755	-0.493	-0.26396	-0.0979	0.16489
105	8.0977	8.3218	8.7053	0.2502	7.8994	8.2973	8.6987	0.2911	-0.3108	-0.02446	0.2998	0.24284

Device Test: 69.19 _EA_GMPS|GMPS/CH3/7/7///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

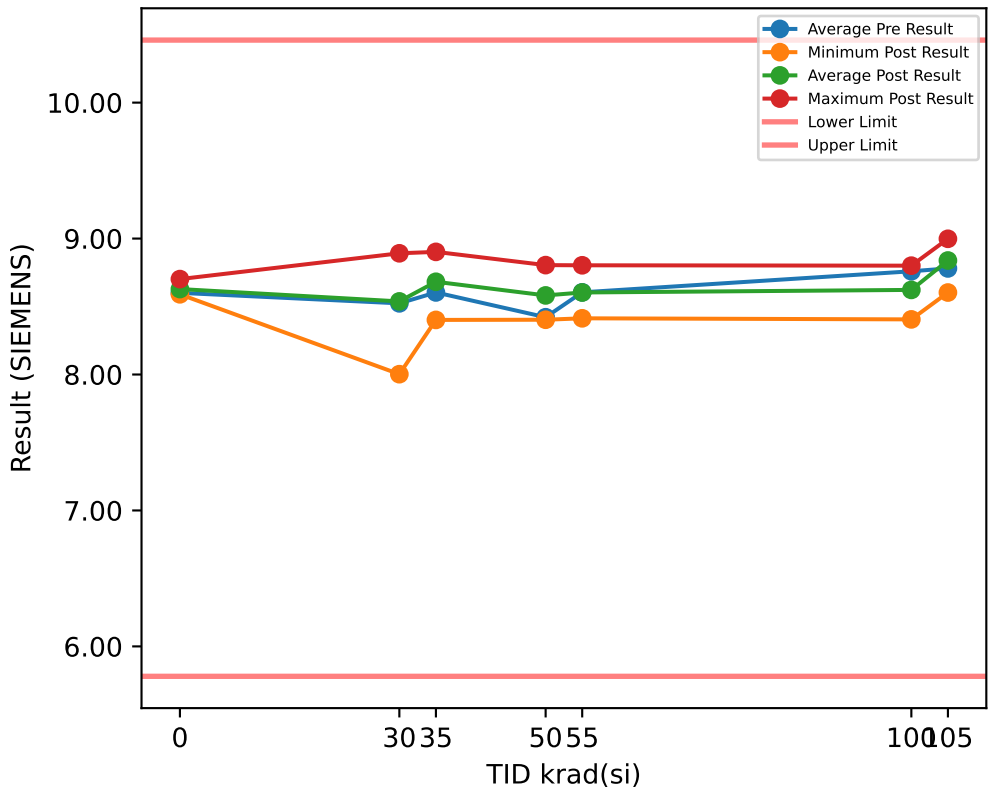
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.1923	8.2909	0.0986
2	0	CU2	8.3976	8.6018	0.2042
3	0	CU3	8.5029	8.4991	-0.0038
11	30	Unbiased-30krad	8.8043	8.9074	0.1031
12	30	Unbiased-30krad	8.4029	8.4082	0.0053
13	30	Unbiased-30krad	8.603	8.7019	0.0989
14	30	Unbiased-30krad	8.8017	9.1011	0.2994
15	30	Unbiased-30krad	8.2989	8.2027	-0.0962
16	35	Biased-30krad	8.5937	8.3989	-0.1948
17	35	Biased-30krad	8.4016	8.4977	0.0961
18	35	Biased-30krad	8.2041	7.9959	-0.2082
19	35	Biased-30krad	8.2989	8.4069	0.108
20	35	Biased-30krad	8.4016	8.5017	0.1001
30	50	Unbiased-50krad	8.1936	8.4938	0.3002
31	50	Unbiased-50krad	8.4068	8.6071	0.2003
32	50	Unbiased-50krad	8.4042	8.3989	-0.0053
33	50	Unbiased-50krad	8.4963	8.3989	-0.0974
34	50	Unbiased-50krad	8.5082	8.6993	0.1911
40	55	Biased-50krad	8.599	8.5979	-0.0011
41	55	Biased-50krad	8.7083	8.9983	0.29
42	55	Biased-50krad	8.1949	8.3002	0.1053
43	55	Biased-50krad	8.2989	8.503	0.2041
44	55	Biased-50krad	8.5042	8.5017	-0.0025
45	100	Unbiased-100krad	8.7017	8.7994	0.0977
46	100	Unbiased-100krad	8.4003	8.6005	0.2002
47	100	Unbiased-100krad	8.599	8.3989	-0.2001
48	100	Unbiased-100krad	8.4016	8.5004	0.0988
49	100	Unbiased-100krad	8.5003	8.503	0.0027
50	105	Biased-100krad	8.5016	8.6084	0.1068
51	105	Biased-100krad	8.5016	8.8969	0.3953
52	105	Biased-100krad	8.8952	8.503	-0.3922
53	105	Biased-100krad	8.6056	8.5017	-0.1039
54	105	Biased-100krad	8.0041	8.2975	0.2934

Test Statistics (SIEMENS)

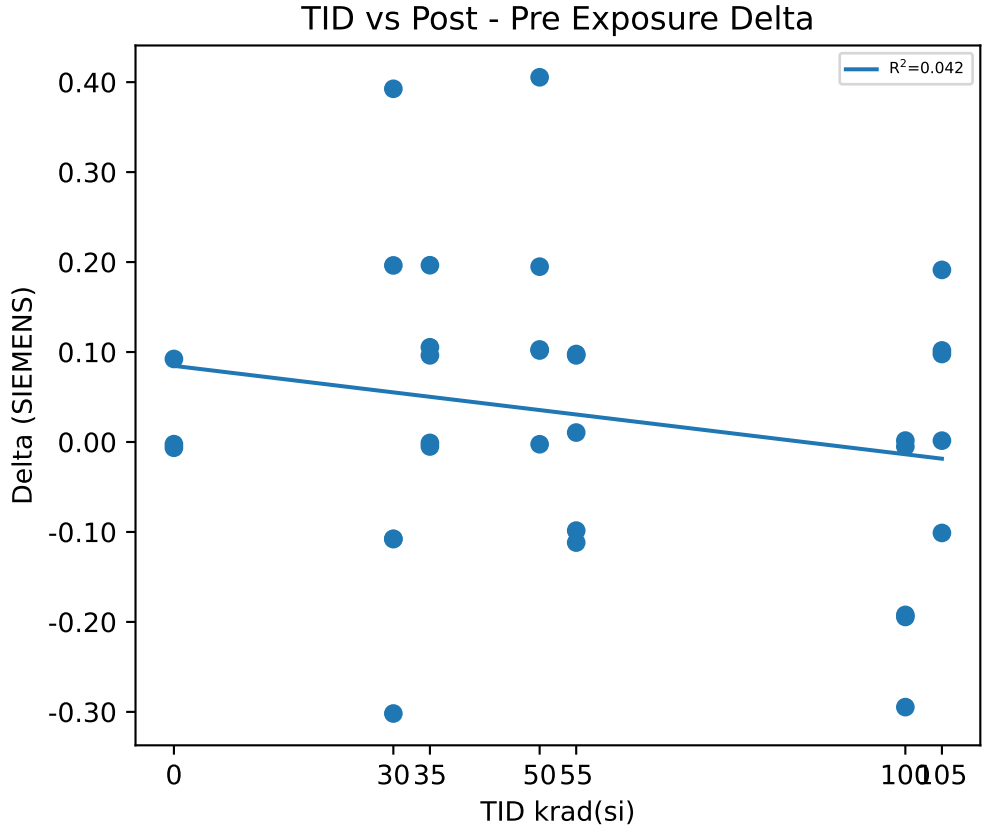
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.1923	8.3643	8.5029	0.15796	8.2909	8.4639	8.6018	0.15841	-0.0038	0.099667	0.2042	0.104
30	8.2989	8.5822	8.8043	0.22932	8.2027	8.6643	9.1011	0.36399	-0.0962	0.0821	0.2994	0.14631
35	8.2041	8.38	8.5937	0.14502	7.9959	8.3602	8.5017	0.20936	-0.2082	-0.01976	0.108	0.16603
50	8.1936	8.4018	8.5082	0.12612	8.3989	8.5196	8.6993	0.13205	-0.0974	0.11778	0.3002	0.16349
55	8.1949	8.4611	8.7083	0.21163	8.3002	8.5802	8.9983	0.2577	-0.0025	0.11916	0.29	0.12831
100	8.4003	8.5206	8.7017	0.13037	8.3989	8.5604	8.7994	0.15142	-0.2001	0.03986	0.2002	0.15124
105	8.0041	8.5016	8.8952	0.32142	8.2975	8.5615	8.8969	0.21874	-0.3922	0.05988	0.3953	0.3164

Device Test: 69.20 _EA_GMPS|GMPS/CH4/7/7///90.9/634//0///@PS_GM

TID vs Result Stats



TID vs Post - Pre Exposure Delta



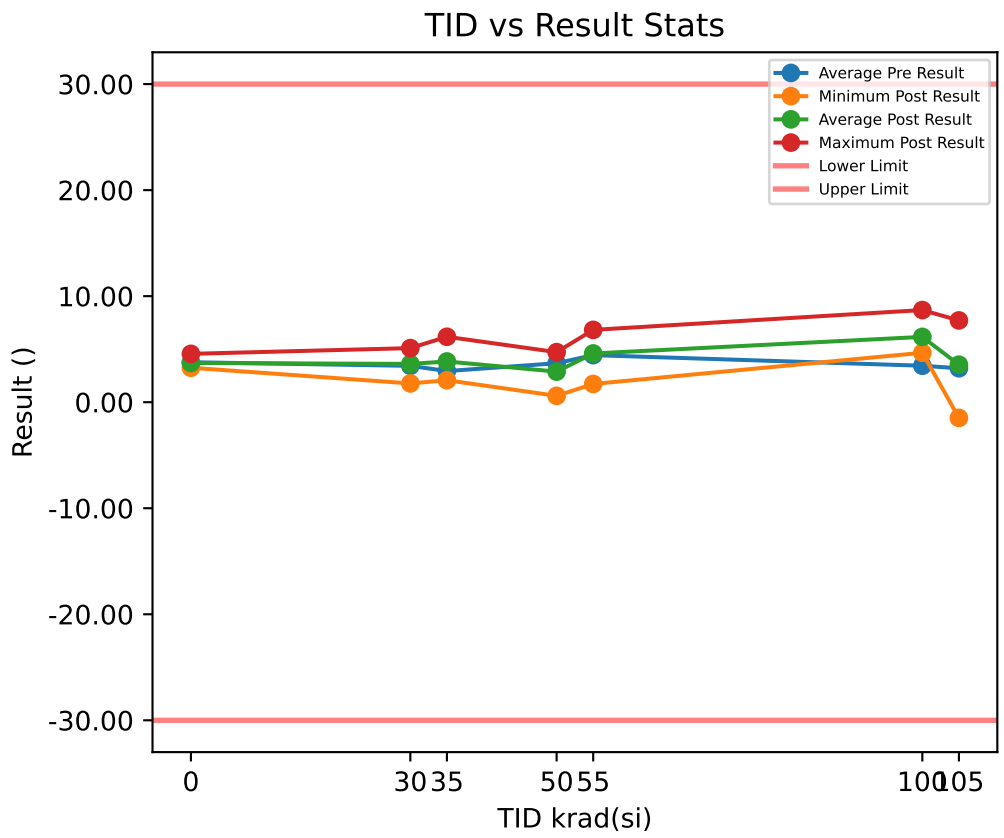
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (SIEMENS))

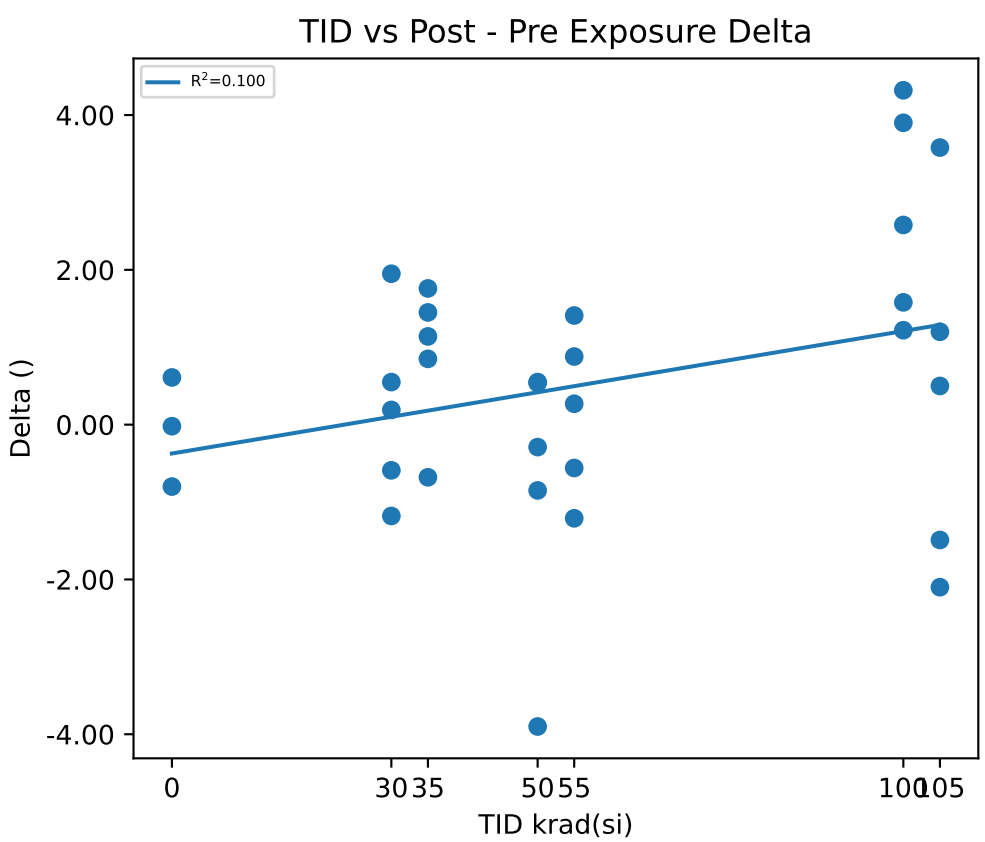
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.5964	8.59	-0.0064
2	0	CU2	8.7043	8.7019	-0.0024
3	0	CU3	8.5016	8.5939	0.0923
11	30	Unbiased-30krad	8.499	8.8916	0.3926
12	30	Unbiased-30krad	8.4016	8.5979	0.1963
13	30	Unbiased-30krad	8.9044	8.7968	-0.1076
14	30	Unbiased-30krad	8.5082	8.4003	-0.1079
15	30	Unbiased-30krad	8.3042	8.0024	-0.3018
16	35	Biased-30krad	8.5121	8.6084	0.0963
17	35	Biased-30krad	8.7017	8.6967	-0.005
18	35	Biased-30krad	8.2963	8.4016	0.1053
19	35	Biased-30krad	8.7056	8.9021	0.1965
20	35	Biased-30krad	8.803	8.802	-0.001
30	50	Unbiased-50krad	8.599	8.7019	0.1029
31	50	Unbiased-50krad	8.703	8.8047	0.1017
32	50	Unbiased-50krad	8.3055	8.5004	0.1949
33	50	Unbiased-50krad	8.5016	8.4991	-0.0025
34	50	Unbiased-50krad	7.9975	8.4029	0.4054
40	55	Biased-50krad	8.8004	8.7019	-0.0985
41	55	Biased-50krad	8.6095	8.4977	-0.1118
42	55	Biased-50krad	8.4029	8.4134	0.0105
43	55	Biased-50krad	8.5042	8.6005	0.0963
44	55	Biased-50krad	8.7056	8.8034	0.0978
45	100	Unbiased-100krad	8.7951	8.5004	-0.2947
46	100	Unbiased-100krad	8.7056	8.7006	-0.005
47	100	Unbiased-100krad	8.5977	8.4055	-0.1922
48	100	Unbiased-100krad	8.8991	8.7046	-0.1945
49	100	Unbiased-100krad	8.7991	8.8007	0.0016
50	105	Biased-100krad	8.8017	8.8995	0.0978
51	105	Biased-100krad	8.8017	8.993	0.1913
52	105	Biased-100krad	8.8004	8.6993	-0.1011
53	105	Biased-100krad	8.8965	8.9983	0.1018
54	105	Biased-100krad	8.6016	8.6031	0.0015

Test Statistics (SIEMENS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.5016	8.6008	8.7043	0.10142	8.59	8.6286	8.7019	0.06351	-0.0064	0.027833	0.0923	0.055866
30	8.3042	8.5235	8.9044	0.22851	8.0024	8.5378	8.8916	0.35406	-0.3018	0.01432	0.3926	0.27656
35	8.2963	8.6037	8.803	0.20161	8.4016	8.6822	8.9021	0.19177	-0.005	0.07842	0.1965	0.084041
50	7.9975	8.4213	8.703	0.27857	8.4029	8.5818	8.8047	0.16551	-0.0025	0.16048	0.4054	0.15371
55	8.4029	8.6045	8.8004	0.15758	8.4134	8.6034	8.8034	0.15571	-0.1118	-0.00114	0.0978	0.10142
100	8.5977	8.7593	8.8991	0.11337	8.4055	8.6224	8.8007	0.16324	-0.2947	-0.13696	0.0016	0.13025
105	8.6016	8.7804	8.8965	0.10812	8.6031	8.8386	8.9983	0.17883	-0.1011	0.05826	0.1913	0.11155

Device Test: 69.21 _EA_GMPS|GMPS_Matching/CH1/7/7///90.9/634//0///@PS_GM_MATCH





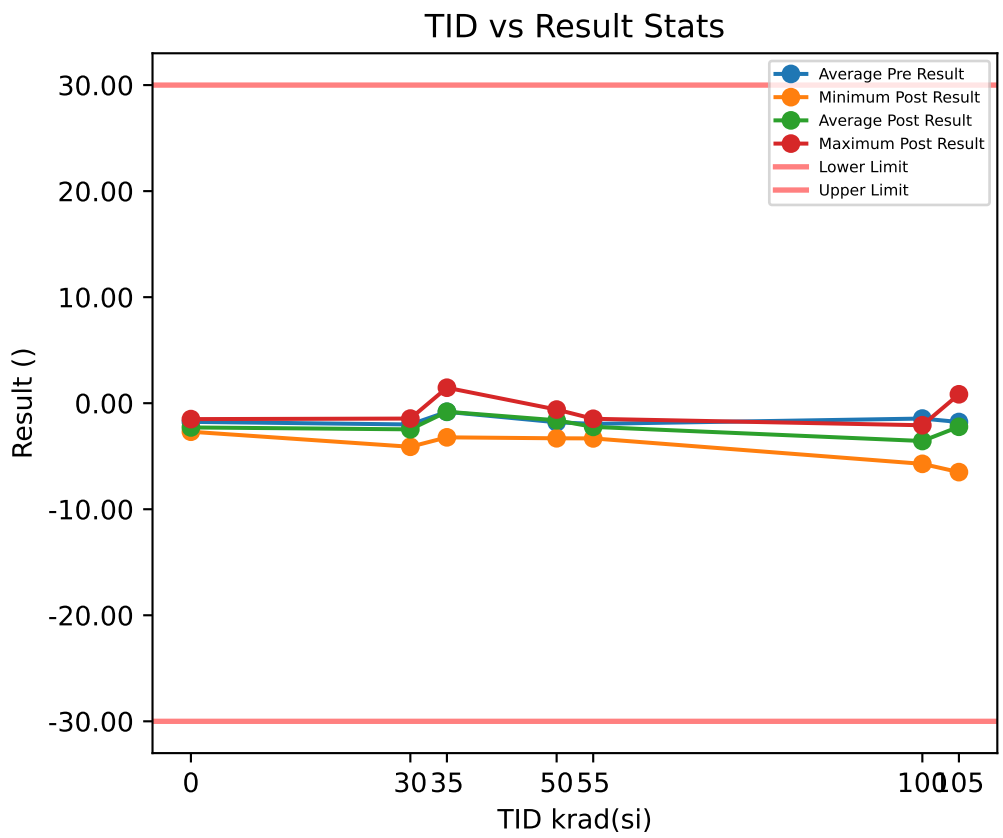
Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

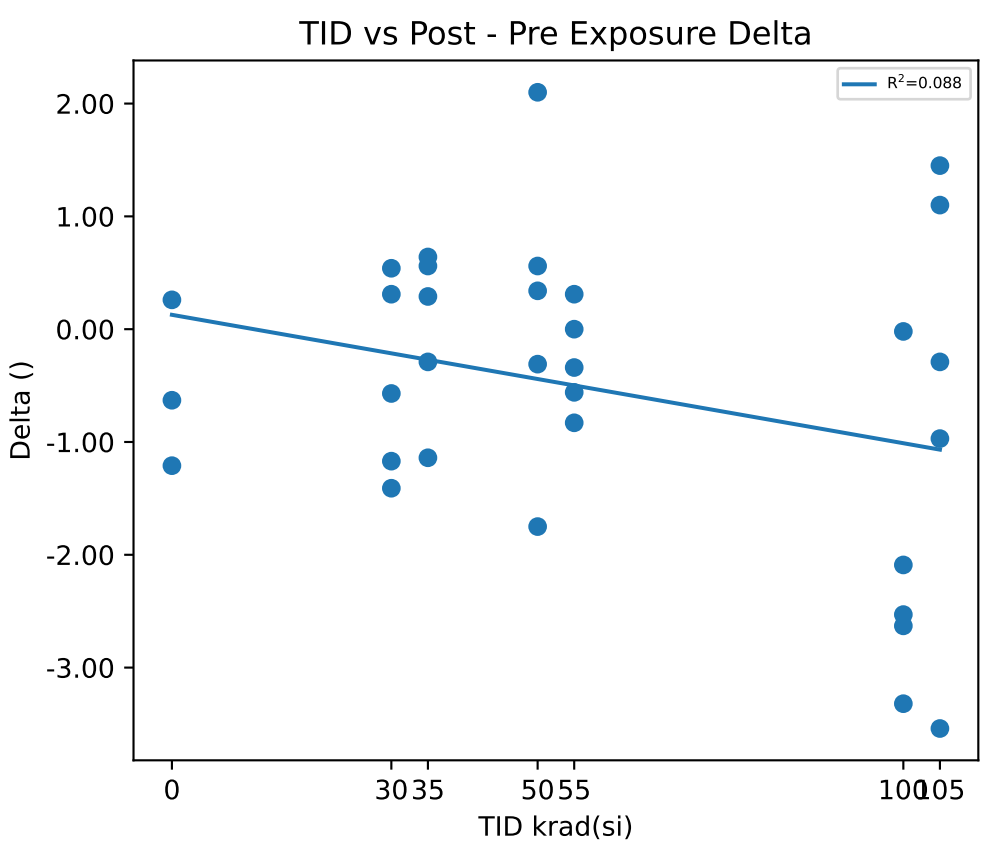
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.95	4.56	0.61
2	0	CU2	3.27	3.25	-0.02
3	0	CU3	4.09	3.29	-0.8
11	30	Unbiased-30krad	2.83	4.78	1.95
12	30	Unbiased-30krad	3.85	3.26	-0.59
13	30	Unbiased-30krad	2.6	3.15	0.55
14	30	Unbiased-30krad	2.95	1.77	-1.18
15	30	Unbiased-30krad	4.91	5.1	0.19
16	35	Biased-30krad	0.62	2.07	1.45
17	35	Biased-30krad	5.03	6.17	1.14
18	35	Biased-30krad	3.58	5.34	1.76
19	35	Biased-30krad	3.13	2.45	-0.68
20	35	Biased-30krad	2.32	3.17	0.85
30	50	Unbiased-50krad	4.18	4.72	0.54
31	50	Unbiased-50krad	2.59	2.3	-0.29
32	50	Unbiased-50krad	4.5	0.6	-3.9
33	50	Unbiased-50krad	3.52	4.07	0.55
34	50	Unbiased-50krad	3.58	2.73	-0.85
40	55	Biased-50krad	3.48	4.89	1.41
41	55	Biased-50krad	2.28	1.72	-0.56
42	55	Biased-50krad	5.94	6.82	0.88
43	55	Biased-50krad	6.38	5.17	-1.21
44	55	Biased-50krad	4.11	4.38	0.27
45	100	Unbiased-100krad	3.08	4.66	1.58
46	100	Unbiased-100krad	2.35	6.67	4.32
47	100	Unbiased-100krad	3.84	5.06	1.22
48	100	Unbiased-100krad	3.13	5.71	2.58
49	100	Unbiased-100krad	4.79	8.69	3.9
50	105	Biased-100krad	0.62	-1.48	-2.1
51	105	Biased-100krad	4.13	7.71	3.58
52	105	Biased-100krad	2.66	3.86	1.2
53	105	Biased-100krad	3.7	4.2	0.5
54	105	Biased-100krad	4.89	3.4	-1.49

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.27	3.77	4.09	0.43863	3.25	3.7	4.56	0.74505	-0.8	-0.07	0.61	0.70633
30	2.6	3.428	4.91	0.95474	1.77	3.612	5.1	1.3517	-1.18	0.184	1.95	1.195
35	0.62	2.936	5.03	1.6264	2.07	3.84	6.17	1.8161	-0.68	0.904	1.76	0.94849
50	2.59	3.674	4.5	0.73245	0.6	2.884	4.72	1.6093	-3.9	-0.79	0.55	1.8365
55	2.28	4.438	6.38	1.711	1.72	4.596	6.82	1.8493	-1.21	0.158	1.41	1.0593
100	2.35	3.438	4.79	0.92145	4.66	6.158	8.69	1.6065	1.22	2.72	4.32	1.3713
105	0.62	3.2	4.89	1.6522	-1.48	3.538	7.71	3.2843	-2.1	0.338	3.58	2.2674

Device Test: 69.22 _EA_GMPS|GMPS_Matching/CH2/7/7///90.9/634//0///@PS_GM_MATCH





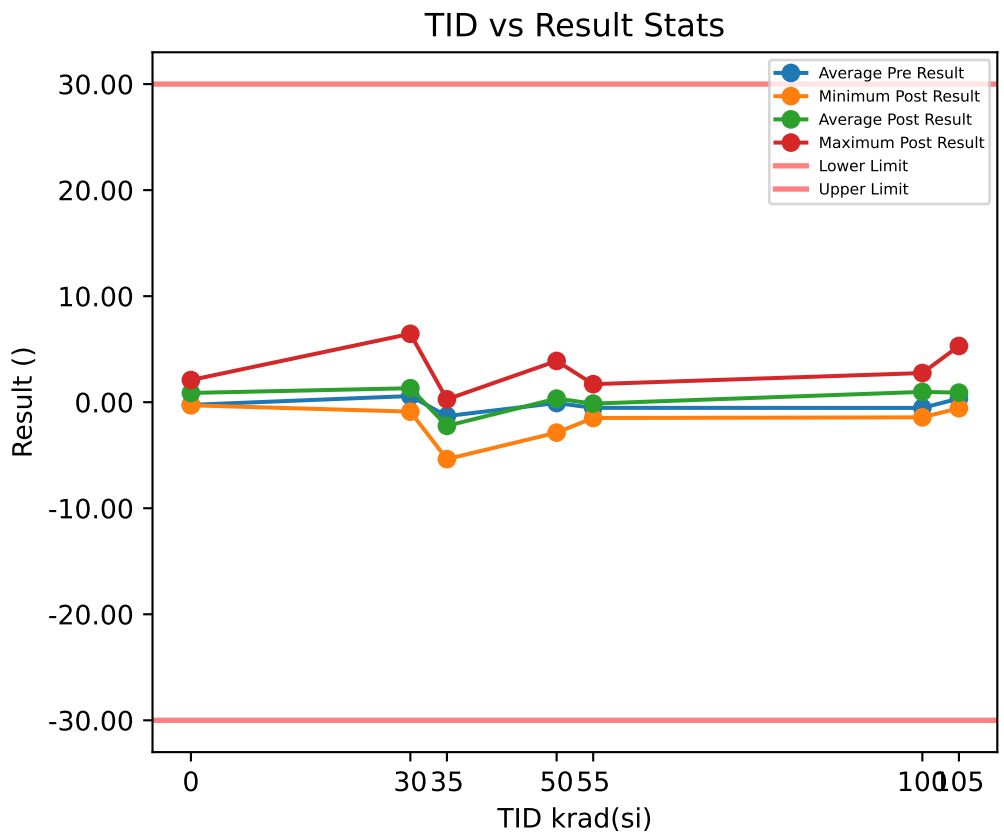
Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

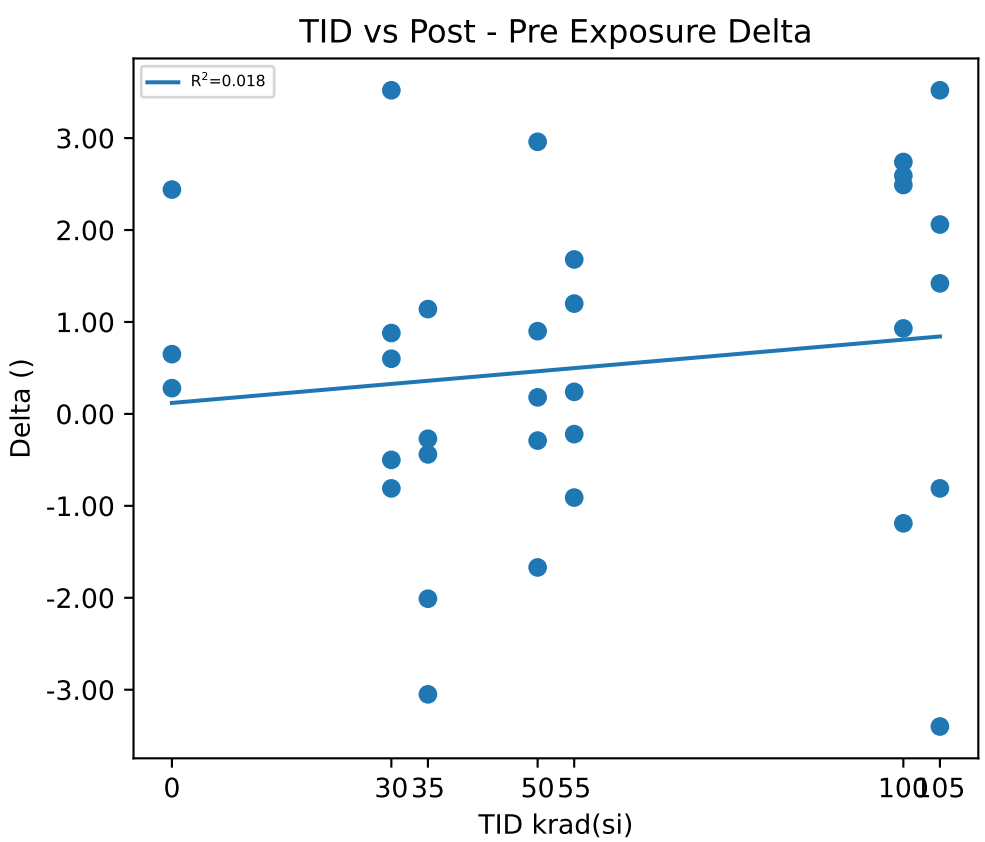
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-2.06	-2.69	-0.63
2	0	CU2	-1.46	-2.67	-1.21
3	0	CU3	-1.76	-1.5	0.26
11	30	Unbiased-30krad	-1.71	-3.12	-1.41
12	30	Unbiased-30krad	-2.08	-1.54	0.54
13	30	Unbiased-30krad	-0.88	-1.45	-0.57
14	30	Unbiased-30krad	-2.94	-4.11	-1.17
15	30	Unbiased-30krad	-2.42	-2.11	0.31
16	35	Biased-30krad	-0.58	-0.29	0.29
17	35	Biased-30krad	-2.08	-3.22	-1.14
18	35	Biased-30krad	-1.19	-0.55	0.64
19	35	Biased-30krad	0.9	1.46	0.56
20	35	Biased-30krad	-1.13	-1.42	-0.29
30	50	Unbiased-50krad	-0.59	-2.34	-1.75
31	50	Unbiased-50krad	-0.88	-1.19	-0.31
32	50	Unbiased-50krad	-2.72	-0.62	2.1
33	50	Unbiased-50krad	-1.16	-0.6	0.56
34	50	Unbiased-50krad	-3.65	-3.31	0.34
40	55	Biased-50krad	-1.17	-2	-0.83
41	55	Biased-50krad	-1.15	-1.71	-0.56
42	55	Biased-50krad	-2.33	-2.67	-0.34
43	55	Biased-50krad	-3.32	-3.32	0
44	55	Biased-50krad	-1.78	-1.47	0.31
45	100	Unbiased-100krad	-1.41	-3.5	-2.09
46	100	Unbiased-100krad	0.01	-2.62	-2.63
47	100	Unbiased-100krad	-2.06	-2.08	-0.02
48	100	Unbiased-100krad	-1.38	-3.91	-2.53
49	100	Unbiased-100krad	-2.4	-5.72	-3.32
50	105	Biased-100krad	-0.61	0.84	1.45
51	105	Biased-100krad	-2.96	-6.5	-3.54
52	105	Biased-100krad	-3.2	-2.1	1.1
53	105	Biased-100krad	-0.85	-1.82	-0.97
54	105	Biased-100krad	-1.25	-1.54	-0.29

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.06	-1.76	-1.46	0.3	-2.69	-2.2867	-1.5	0.68135	-1.21	-0.52667	0.26	0.74043
30	-2.94	-2.006	-0.88	0.77536	-4.11	-2.466	-1.45	1.1343	-1.41	-0.46	0.54	0.8677
35	-2.08	-0.816	0.9	1.0996	-3.22	-0.804	1.46	1.7081	-1.14	0.012	0.64	0.73998
50	-3.65	-1.8	-0.59	1.3218	-3.31	-1.612	-0.6	1.1832	-1.75	0.188	2.1	1.3983
55	-3.32	-1.95	-1.15	0.9081	-3.32	-2.234	-1.47	0.7554	-0.83	-0.284	0.31	0.45026
100	-2.4	-1.448	0.01	0.92367	-5.72	-3.566	-2.08	1.4023	-3.32	-2.118	-0.02	1.2529
105	-3.2	-1.774	-0.61	1.2169	-6.5	-2.224	0.84	2.6608	-3.54	-0.45	1.45	1.991

Device Test: 69.23 _EA_GMPS|GMPS_Matching/CH3/7/7///90.9/634//0///@PS_GM_MATCH





Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

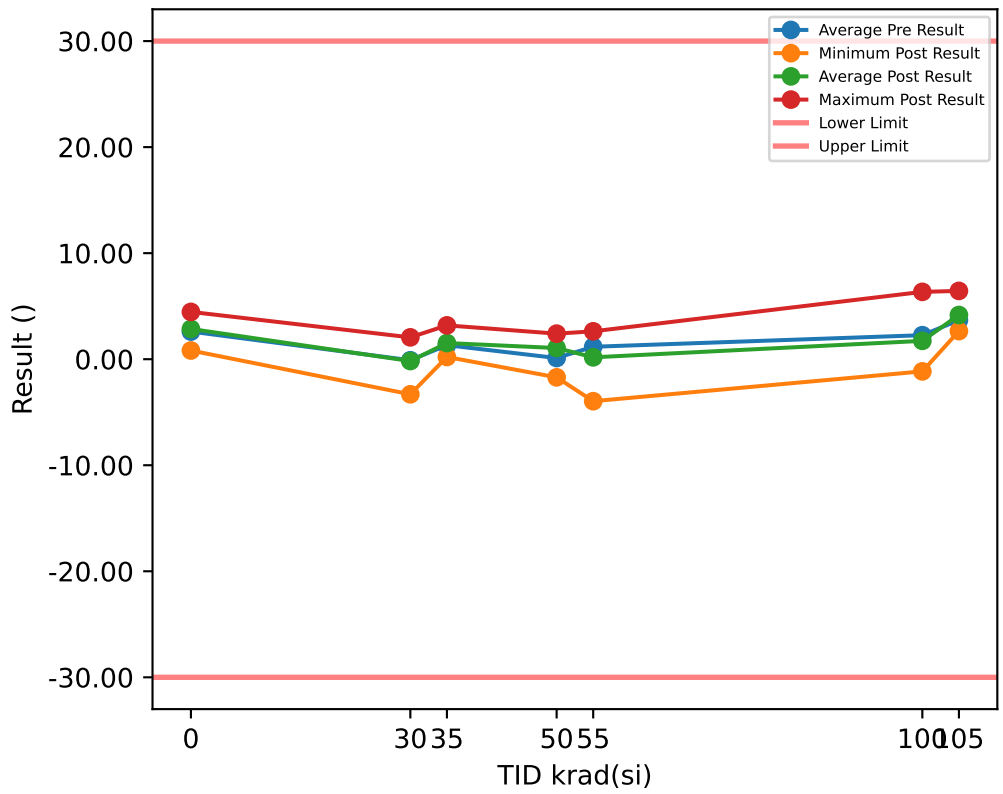
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.17	0.82	0.65
2	0	CU2	-0.35	2.09	2.44
3	0	CU3	-0.57	-0.29	0.28
11	30	Unbiased-30krad	0.58	1.46	0.88
12	30	Unbiased-30krad	0.31	-0.19	-0.5
13	30	Unbiased-30krad	-0.84	-0.24	0.6
14	30	Unbiased-30krad	2.93	6.45	3.52
15	30	Unbiased-30krad	-0.08	-0.89	-0.81
16	35	Biased-30krad	0.53	-1.48	-2.01
17	35	Biased-30krad	-0.87	0.27	1.14
18	35	Biased-30krad	-1.2	-4.25	-3.05
19	35	Biased-30krad	-4.93	-5.37	-0.44
20	35	Biased-30krad	-0.06	-0.33	-0.27
30	50	Unbiased-50krad	-3	-0.04	2.96
31	50	Unbiased-50krad	-0.83	0.07	0.9
32	50	Unbiased-50krad	0.93	0.64	-0.29
33	50	Unbiased-50krad	-1.2	-2.87	-1.67
34	50	Unbiased-50krad	3.71	3.89	0.18
40	55	Biased-50krad	-1.14	-0.9	0.24
41	55	Biased-50krad	0.02	1.7	1.68
42	55	Biased-50krad	-1.27	-1.49	-0.22
43	55	Biased-50krad	0.27	1.47	1.2
44	55	Biased-50krad	-0.54	-1.45	-0.91
45	100	Unbiased-100krad	-0.26	2.33	2.59
46	100	Unbiased-100krad	-2.36	-1.43	0.93
47	100	Unbiased-100krad	0.29	-0.9	-1.19
48	100	Unbiased-100krad	-0.38	2.11	2.49
49	100	Unbiased-100krad	0.01	2.75	2.74
50	105	Biased-100krad	0.6	-0.21	-0.81
51	105	Biased-100krad	1.78	5.3	3.52
52	105	Biased-100krad	3.73	0.33	-3.4
53	105	Biased-100krad	-1.99	-0.57	1.42
54	105	Biased-100krad	-2.39	-0.33	2.06

Test Statistics ()

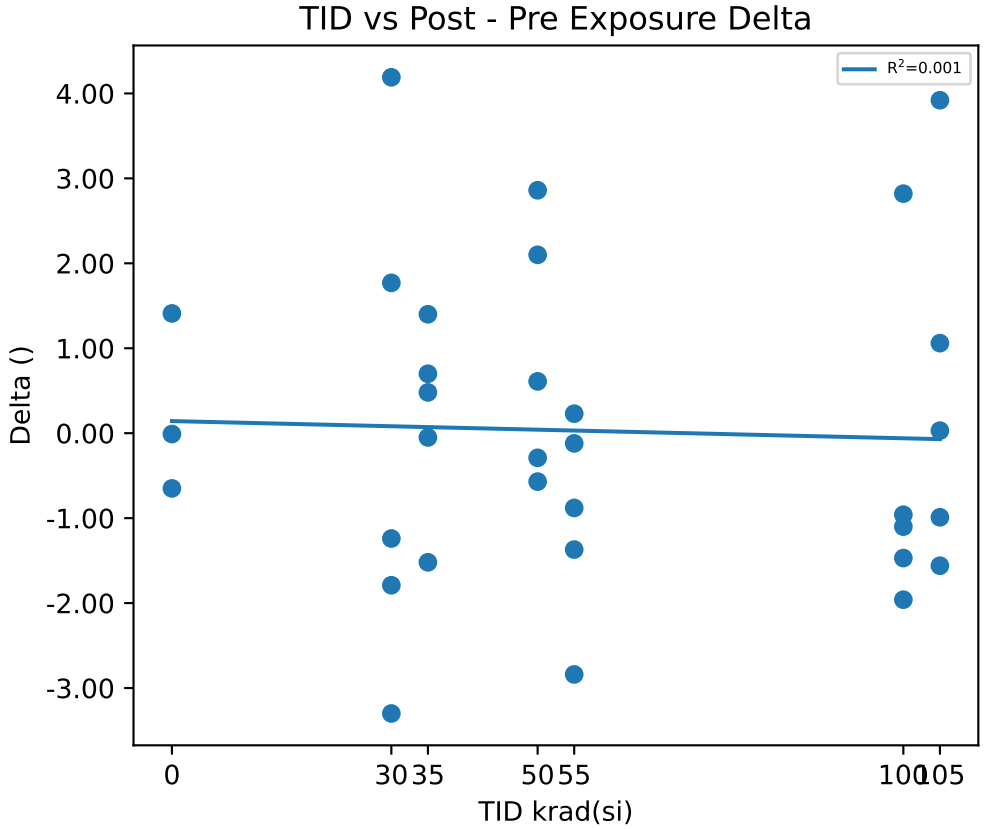
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.57	-0.25	0.17	0.38	-0.29	0.87333	2.09	1.1909	0.28	1.1233	2.44	1.1552
30	-0.84	0.58	2.93	1.4184	-0.89	1.318	6.45	2.9973	-0.81	0.738	3.52	1.7108
35	-4.93	-1.306	0.53	2.1365	-5.37	-2.232	0.27	2.4679	-3.05	-0.926	1.14	1.6295
50	-3	-0.078	3.71	2.5361	-2.87	0.338	3.89	2.409	-1.67	0.416	2.96	1.7038
55	-1.27	-0.532	0.27	0.68233	-1.49	-0.134	1.7	1.5885	-0.91	0.398	1.68	1.0493
100	-2.36	-0.54	0.29	1.0497	-1.43	0.972	2.75	1.9732	-1.19	1.512	2.74	1.6782
105	-2.39	0.346	3.73	2.5746	-0.57	0.904	5.3	2.4795	-3.4	0.558	3.52	2.7069

Device Test: 69.24 _EA_GMPS|GMPS_Matching/CH4/7/7///90.9/634//0///@PS_GM_MATCH

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = -30.0, Upper Limit = 30.0 ())

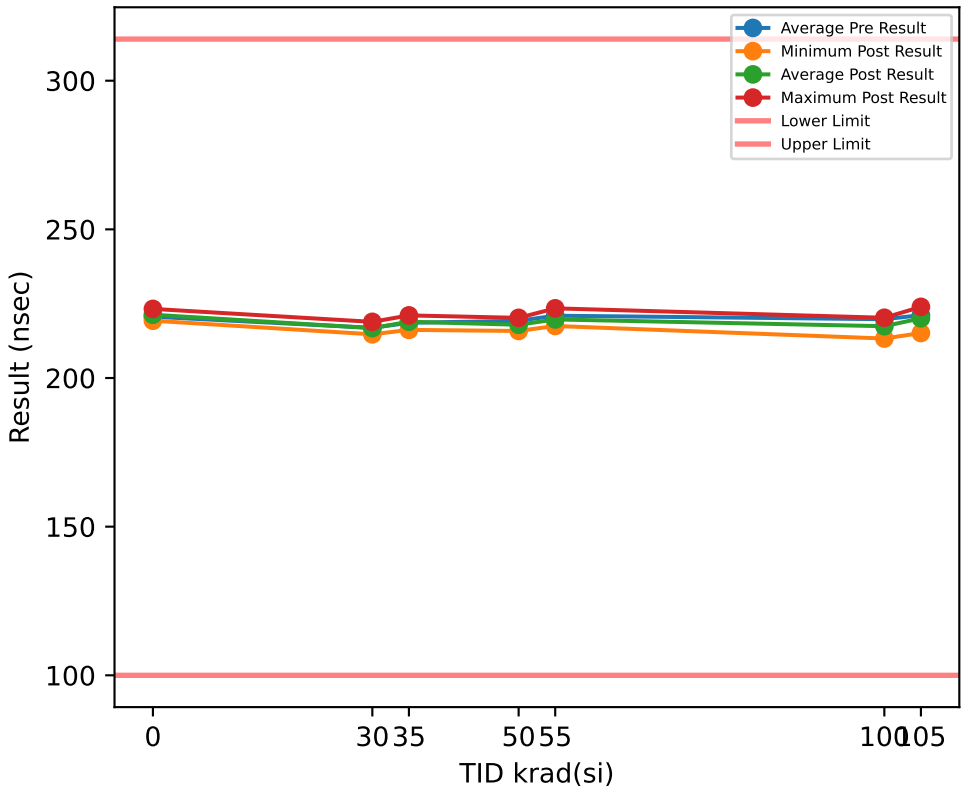
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.11	4.46	-0.65
2	0	CU2	3.29	3.28	-0.01
3	0	CU3	-0.59	0.82	1.41
11	30	Unbiased-30krad	-2.91	1.28	4.19
12	30	Unbiased-30krad	0.29	2.06	1.77
13	30	Unbiased-30krad	2.64	0.85	-1.79
14	30	Unbiased-30krad	-0.51	-1.75	-1.24
15	30	Unbiased-30krad	-0.01	-3.31	-3.3
16	35	Biased-30krad	-0.42	0.98	1.4
17	35	Biased-30krad	2.67	2.62	-0.05
18	35	Biased-30krad	-0.09	0.61	0.7
19	35	Biased-30krad	-0.27	0.21	0.48
20	35	Biased-30krad	4.71	3.19	-1.52
30	50	Unbiased-50krad	1.8	2.41	0.61
31	50	Unbiased-50krad	2.66	2.37	-0.29
32	50	Unbiased-50krad	-0.25	1.85	2.1
33	50	Unbiased-50krad	-1.14	-1.71	-0.57
34	50	Unbiased-50krad	-2.51	0.35	2.86
40	55	Biased-50krad	1.18	0.3	-0.88
41	55	Biased-50krad	-1.12	-3.96	-2.84
42	55	Biased-50krad	1.23	-0.14	-1.37
43	55	Biased-50krad	2.75	2.63	-0.12
44	55	Biased-50krad	1.82	2.05	0.23
45	100	Unbiased-100krad	0.81	-1.15	-1.96
46	100	Unbiased-100krad	1.19	-0.28	-1.47
47	100	Unbiased-100krad	0.27	-0.83	-1.1
48	100	Unbiased-100krad	5.52	4.56	-0.96
49	100	Unbiased-100krad	3.53	6.35	2.82
50	105	Biased-100krad	4.16	3.17	-0.99
51	105	Biased-100krad	5.38	6.44	1.06
52	105	Biased-100krad	2.62	2.65	0.03
53	105	Biased-100krad	1.32	5.24	3.92
54	105	Biased-100krad	4.9	3.34	-1.56

Test Statistics ()

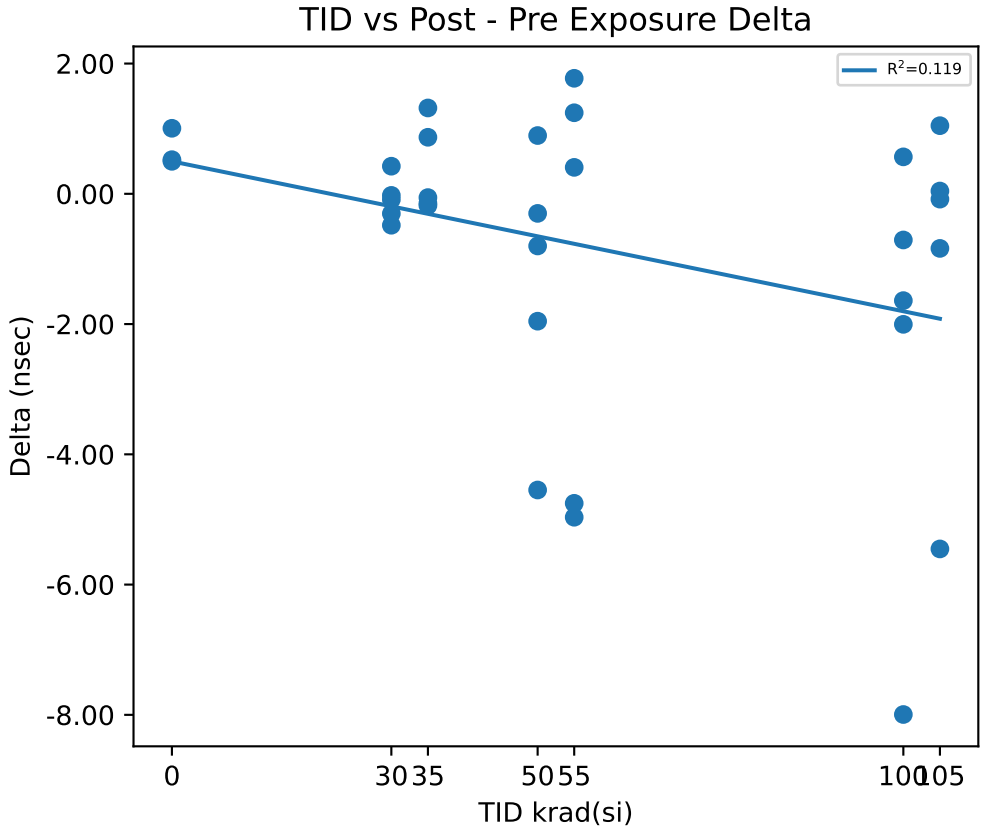
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.59	2.6033	5.11	2.9114	0.82	2.8533	4.46	1.8571	-0.65	0.25	1.41	1.0543
30	-2.91	-0.1	2.64	1.9832	-3.31	-0.174	2.06	2.2623	-3.3	-0.074	4.19	3.0122
35	-0.42	1.32	4.71	2.2835	0.21	1.522	3.19	1.3072	-1.52	0.202	1.4	1.0942
50	-2.51	0.112	2.66	2.1163	-1.71	1.054	2.41	1.7564	-0.57	0.942	2.86	1.4945
55	-1.12	1.172	2.75	1.4289	-3.96	0.176	2.63	2.5863	-2.84	-0.996	0.23	1.2067
100	0.27	2.264	5.52	2.205	-1.15	1.73	6.35	3.4728	-1.96	-0.534	2.82	1.9145
105	1.32	3.676	5.38	1.6809	2.65	4.168	6.44	1.6045	-1.56	0.492	3.92	2.1618

Device Test: 72.13 _EXT_CLOCK|Delay/SYNC_to_SW1/3/3/////1.8///@SYNC_SW_DELAY_VIN_3V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 100.0, Upper Limit = 314.0 (nsec))

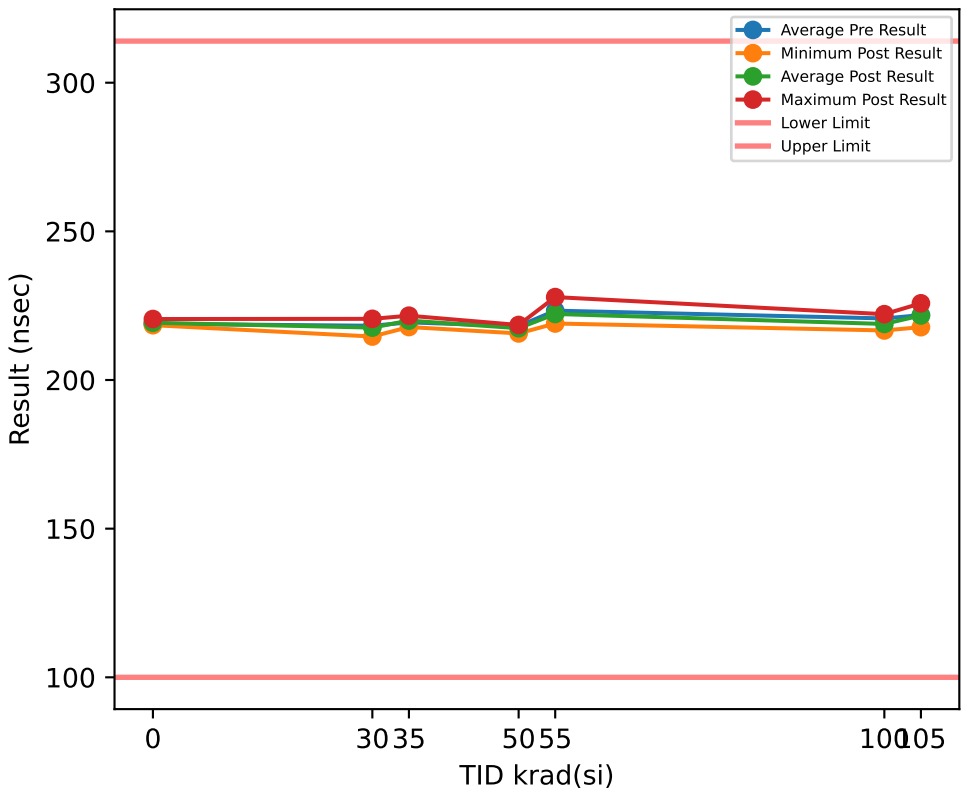
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	218.27	219.28	1.0062
2	0	CU2	222.72	223.24	0.5241
3	0	CU3	220.86	221.36	0.4988
11	30	Unbiased-30krad	215.18	214.7	-0.4825
12	30	Unbiased-30krad	219.19	218.89	-0.3038
13	30	Unbiased-30krad	215.65	216.08	0.424
14	30	Unbiased-30krad	216.54	216.52	-0.0241
15	30	Unbiased-30krad	217.81	217.72	-0.0888
16	35	Biased-30krad	215.63	216.5	0.8682
17	35	Biased-30krad	218.64	219.96	1.3182
18	35	Biased-30krad	221.12	221.06	-0.0578
19	35	Biased-30krad	216.34	216.19	-0.1459
20	35	Biased-30krad	221.12	220.94	-0.1799
30	50	Unbiased-50krad	218.05	218.95	0.8949
31	50	Unbiased-50krad	222.45	217.9	-4.5476
32	50	Unbiased-50krad	221.04	220.24	-0.8007
33	50	Unbiased-50krad	217.78	215.82	-1.9557
34	50	Unbiased-50krad	216.93	216.63	-0.3006
40	55	Biased-50krad	216.73	218.5	1.7738
41	55	Biased-50krad	222.26	217.5	-4.7521
42	55	Biased-50krad	222.95	217.99	-4.9659
43	55	Biased-50krad	220.68	221.09	0.4061
44	55	Biased-50krad	222.19	223.43	1.2446
45	100	Unbiased-100krad	222.02	220.01	-2.0042
46	100	Unbiased-100krad	219.5	218.8	-0.7086
47	100	Unbiased-100krad	219.7	220.26	0.5674
48	100	Unbiased-100krad	216.41	214.78	-1.6397
49	100	Unbiased-100krad	221.27	213.28	-7.9948
50	105	Biased-100krad	220.59	215.13	-5.4526
51	105	Biased-100krad	222.88	223.93	1.0462
52	105	Biased-100krad	219.11	219.15	0.0427
53	105	Biased-100krad	223.7	222.87	-0.8382
54	105	Biased-100krad	219.38	219.3	-0.0818

Test Statistics (nsec)

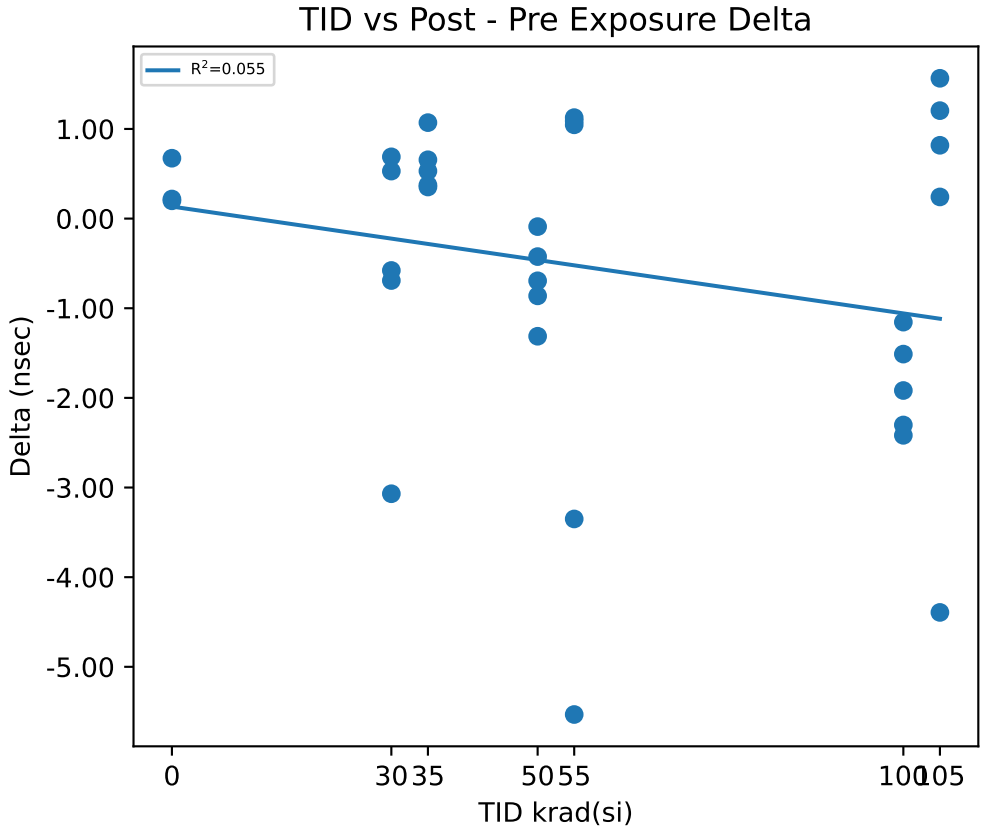
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	218.27	220.62	222.72	2.2344	219.28	221.29	223.24	1.984	0.4988	0.67637	1.0062	0.28592
30	215.18	216.88	219.19	1.637	214.7	216.78	218.89	1.5993	-0.4825	-0.09504	0.424	0.34212
35	215.63	218.57	221.12	2.5787	216.19	218.93	221.06	2.3991	-0.1799	0.36056	1.3182	0.68891
50	216.93	219.25	222.45	2.3668	215.82	217.91	220.24	1.7656	-4.5476	-1.3419	0.8949	2.0636
55	216.73	220.96	222.95	2.5075	217.5	219.7	223.43	2.5028	-4.9659	-1.2587	1.7738	3.3235
100	216.41	219.78	222.02	2.1589	213.28	217.43	220.26	3.1962	-7.9948	-2.356	0.5674	3.305
105	219.11	221.13	223.7	2.0684	215.13	220.08	223.93	3.4815	-5.4526	-1.0567	1.0462	2.5472

Device Test: 72.14 _EXT_CLOCK|Delay/SYNC_to_SW2/3/3/////1.8///@SYNC_SW_DELAY_VIN_3V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



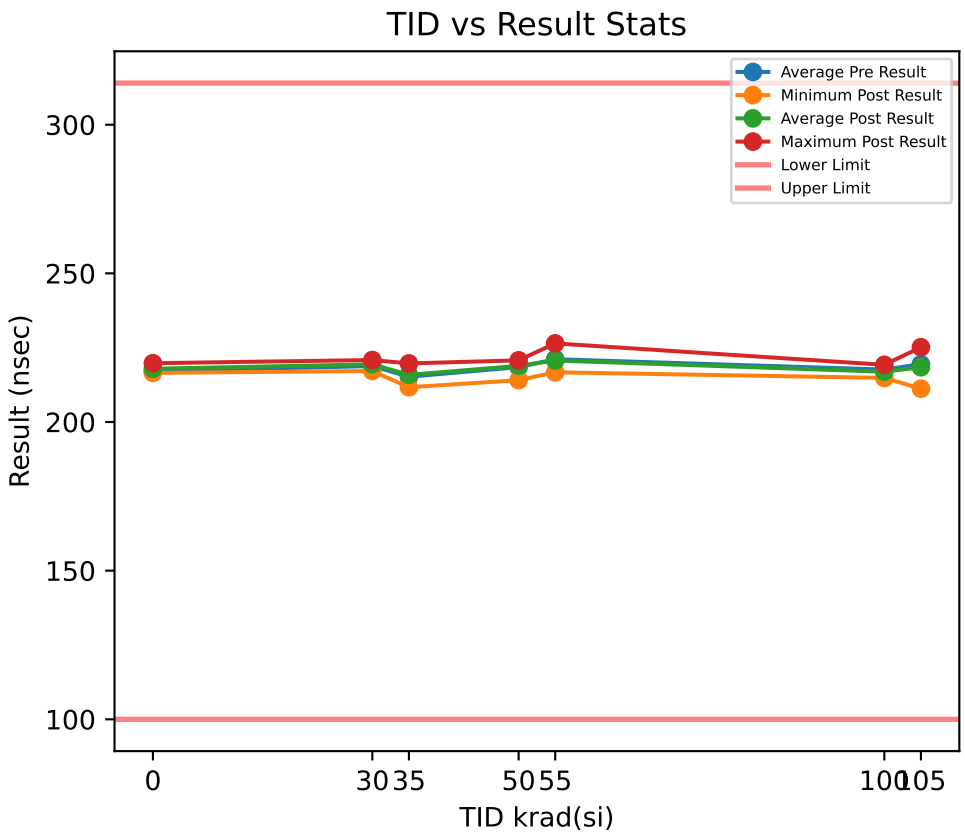
Test Results (Lower Limit = 100.0, Upper Limit = 314.0 (nsec))

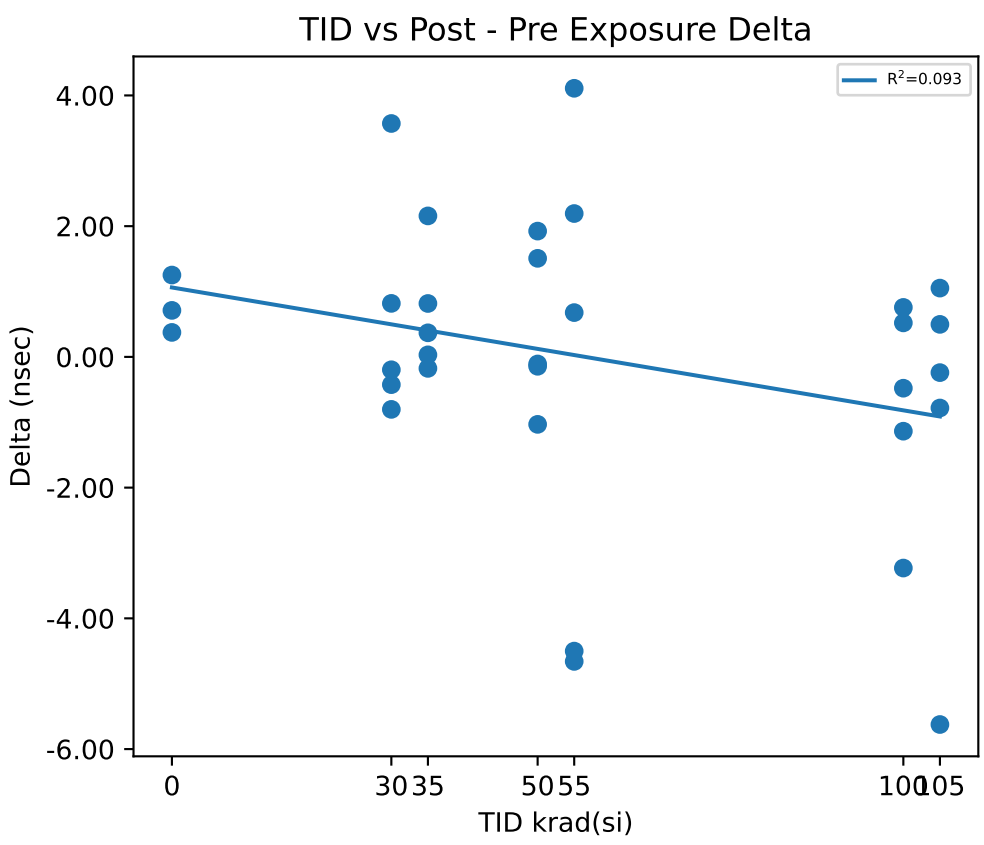
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	218.16	218.83	0.6735
2	0	CU2	220.29	220.51	0.2185
3	0	CU3	218.25	218.44	0.1983
11	30	Unbiased-30krad	218.3	217.72	-0.5786
12	30	Unbiased-30krad	217.7	214.63	-3.0693
13	30	Unbiased-30krad	220.04	220.57	0.5299
14	30	Unbiased-30krad	217.76	218.45	0.6889
15	30	Unbiased-30krad	217.45	216.76	-0.6909
16	35	Biased-30krad	216.75	217.82	1.0705
17	35	Biased-30krad	220.44	220.79	0.3524
18	35	Biased-30krad	221.1	221.63	0.5307
19	35	Biased-30krad	218.85	219.51	0.6561
20	35	Biased-30krad	219.81	220.19	0.3745
30	50	Unbiased-50krad	216.73	216.04	-0.6939
31	50	Unbiased-50krad	219.75	218.44	-1.3125
32	50	Unbiased-50krad	218.93	218.51	-0.4239
33	50	Unbiased-50krad	219.34	218.48	-0.862
34	50	Unbiased-50krad	215.76	215.67	-0.0894
40	55	Biased-50krad	226.76	227.89	1.1263
41	55	Biased-50krad	224.75	219.22	-5.532
42	55	Biased-50krad	222.36	219.01	-3.3506
43	55	Biased-50krad	221.09	222.18	1.0892
44	55	Biased-50krad	221.72	222.76	1.0461
45	100	Unbiased-100krad	220.1	218.95	-1.155
46	100	Unbiased-100krad	221.74	219.43	-2.3023
47	100	Unbiased-100krad	224.06	222.14	-1.9177
48	100	Unbiased-100krad	218.18	216.67	-1.5116
49	100	Unbiased-100krad	219.48	217.06	-2.4178
50	105	Biased-100krad	222.17	217.78	-4.3931
51	105	Biased-100krad	222.53	223.73	1.2043
52	105	Biased-100krad	220.79	221.03	0.2416
53	105	Biased-100krad	224.23	225.8	1.5651
54	105	Biased-100krad	219.41	220.22	0.8178

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	218.16	218.9	220.29	1.2077	218.44	219.26	220.51	1.0989	0.1983	0.36343	0.6735	0.26872
30	217.45	218.25	220.04	1.0501	214.63	217.62	220.57	2.1864	-3.0693	-0.624	0.6889	1.5034
35	216.75	219.39	221.1	1.6933	217.82	219.99	221.63	1.4421	0.3524	0.59684	1.0705	0.29216
50	215.76	218.1	219.75	1.7523	215.67	217.43	218.51	1.4401	-1.3125	-0.67634	-0.0894	0.46035
55	221.09	223.34	226.76	2.3655	219.01	222.21	227.89	3.5963	-5.532	-1.1242	1.1263	3.1249
100	218.18	220.71	224.06	2.2661	216.67	218.85	222.14	2.1874	-2.4178	-1.8609	-1.155	0.53116
105	219.41	221.82	224.23	1.8255	217.78	221.71	225.8	3.1197	-4.3931	-0.11286	1.5651	2.4425

Device Test: 72.15 _EXT_CLOCK|Delay/SYNC_to_SW3/3/3/////1.8///@SYNC_SW_DELAY_VIN_3V





Test Results (Lower Limit = 100.0, Upper Limit = 314.0 (nsec))

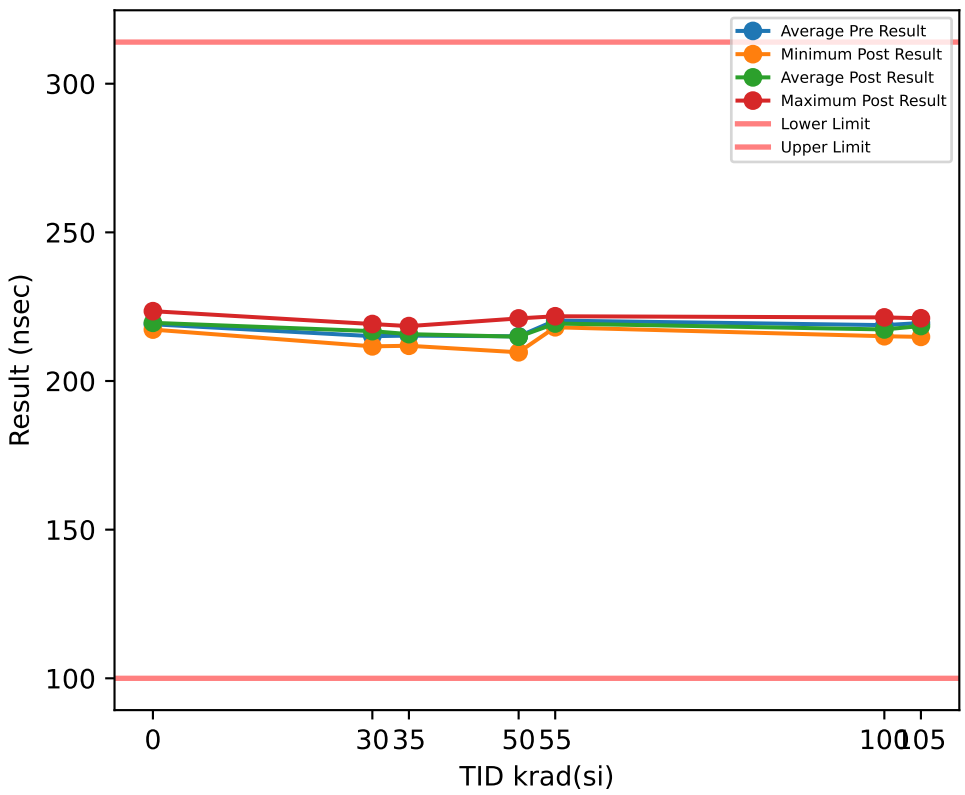
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	218.52	219.77	1.2522
2	0	CU2	217.05	217.42	0.3746
3	0	CU3	215.83	216.54	0.7116
11	30	Unbiased-30krad	215.5	219.07	3.5709
12	30	Unbiased-30krad	216.32	217.14	0.8187
13	30	Unbiased-30krad	219.88	219.69	-0.1969
14	30	Unbiased-30krad	221.08	220.28	-0.803
15	30	Unbiased-30krad	221.27	220.85	-0.4245
16	35	Biased-30krad	216.74	216.78	0.0314
17	35	Biased-30krad	219.34	219.7	0.3683
18	35	Biased-30krad	209.54	211.7	2.1568
19	35	Biased-30krad	215.21	215.04	-0.1756
20	35	Biased-30krad	215.29	216.11	0.8171
30	50	Unbiased-50krad	212.15	214.07	1.9245
31	50	Unbiased-50krad	220.13	220.03	-0.1083
32	50	Unbiased-50krad	220.52	220.37	-0.1437
33	50	Unbiased-50krad	217.75	219.26	1.5079
34	50	Unbiased-50krad	221.78	220.74	-1.0322
40	55	Biased-50krad	218.15	222.25	4.1093
41	55	Biased-50krad	224.95	220.29	-4.6586
42	55	Biased-50krad	221.22	216.72	-4.501
43	55	Biased-50krad	215.54	217.73	2.1932
44	55	Biased-50krad	225.77	226.45	0.6777
45	100	Unbiased-100krad	222.39	219.16	-3.2303
46	100	Unbiased-100krad	217.16	216.02	-1.1368
47	100	Unbiased-100krad	218.48	219.24	0.7571
48	100	Unbiased-100krad	215.32	214.84	-0.479
49	100	Unbiased-100krad	214.81	215.33	0.5203
50	105	Biased-100krad	223.77	218.14	-5.624
51	105	Biased-100krad	219	218.76	-0.2405
52	105	Biased-100krad	211.99	211.21	-0.782
53	105	Biased-100krad	224.1	225.15	1.0525
54	105	Biased-100krad	218.4	218.9	0.4976

Test Statistics (nsec)

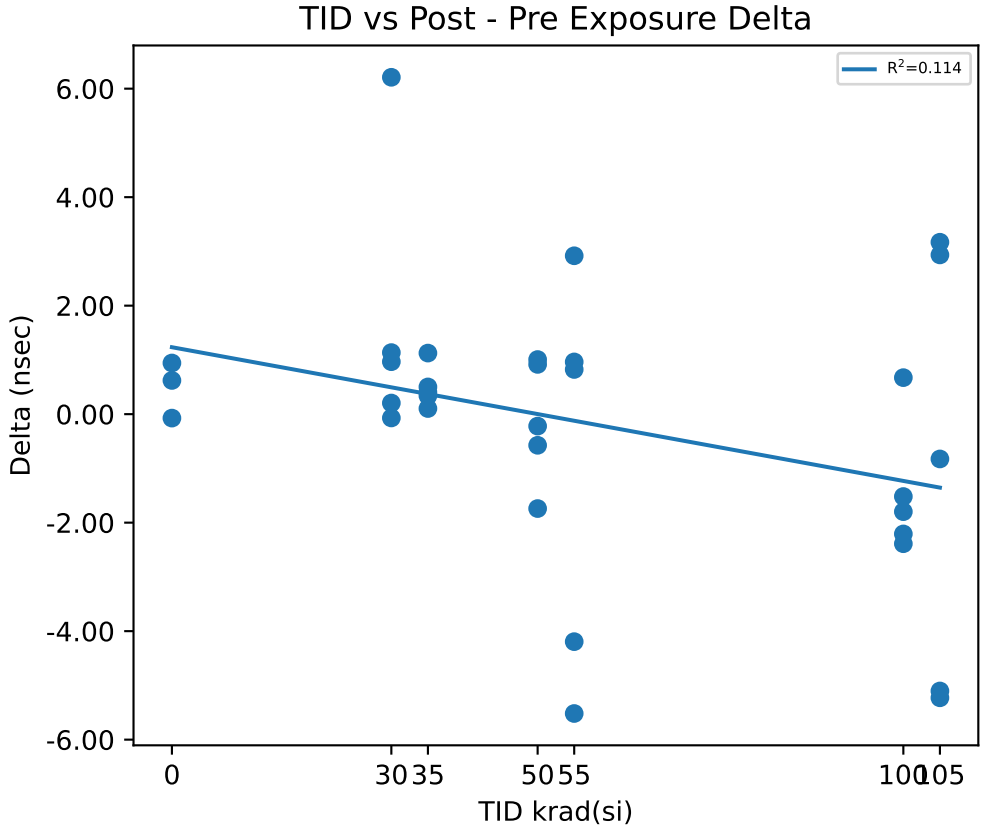
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	215.83	217.13	218.52	1.3477	216.54	217.91	219.77	1.6707	0.3746	0.77947	1.2522	0.44272
30	215.5	218.81	221.27	2.7163	217.14	219.4	220.85	1.427	-0.803	0.59304	3.5709	1.7697
35	209.54	215.22	219.34	3.5895	211.7	215.86	219.7	2.902	-0.1756	0.6396	2.1568	0.92756
50	212.15	218.47	221.78	3.8207	214.07	218.9	220.74	2.7517	-1.0322	0.42964	1.9245	1.2402
55	215.54	221.13	225.77	4.3666	216.72	220.69	226.45	3.8804	-4.6586	-0.43588	4.1093	3.9739
100	214.81	217.63	222.39	3.0364	214.84	216.92	219.24	2.1244	-3.2303	-0.71374	0.7571	1.601
105	211.99	219.45	224.1	4.9299	211.21	218.43	225.15	4.9431	-5.624	-1.0193	1.0525	2.6674

Device Test: 72.16 _EXT_CLOCK|Delay/SYNC_to_SW4/3/3/////1.8///@SYNC_SW_DELAY_VIN_3V

TID vs Result Stats



TID vs Post - Pre Exposure Delta



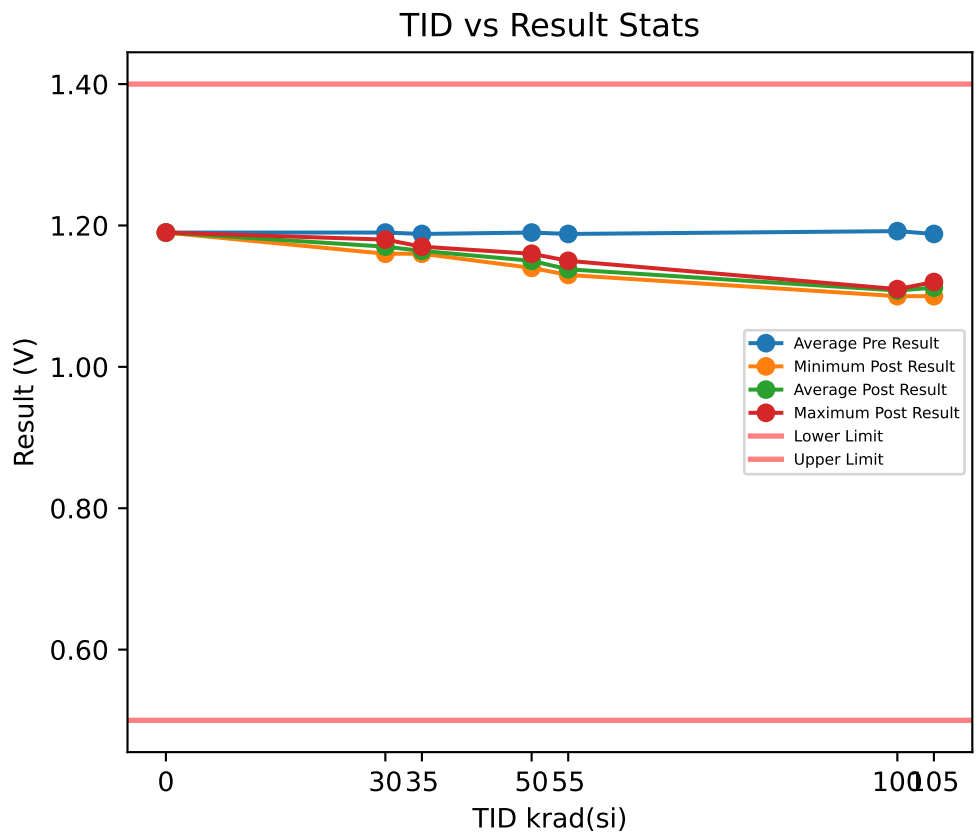
Test Results (Lower Limit = 100.0, Upper Limit = 314.0 (nsec))

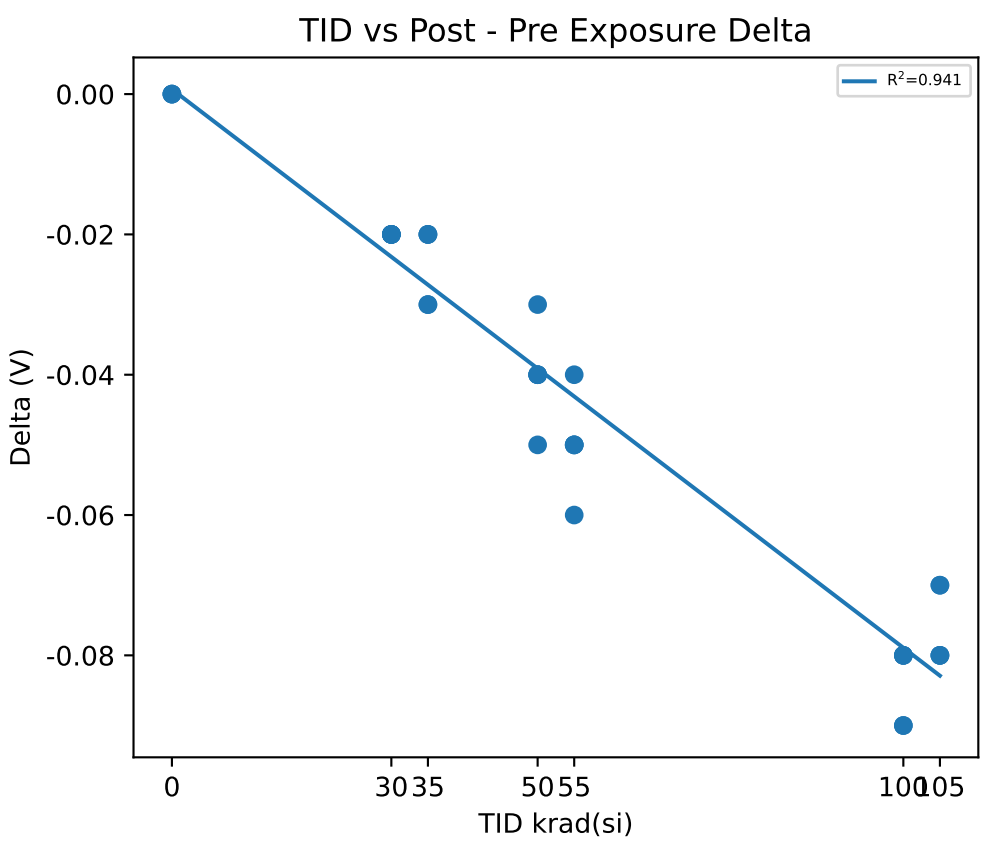
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	217	217.95	0.943
2	0	CU2	216.68	217.3	0.6214
3	0	CU3	223.56	223.48	-0.0727
11	30	Unbiased-30krad	217.32	218.28	0.967
12	30	Unbiased-30krad	211.73	211.66	-0.07
13	30	Unbiased-30krad	212.96	219.17	6.2097
14	30	Unbiased-30krad	218.36	218.57	0.2051
15	30	Unbiased-30krad	215.04	216.18	1.1349
16	35	Biased-30krad	217.42	217.92	0.5018
17	35	Biased-30krad	218.13	218.47	0.3397
18	35	Biased-30krad	210.73	211.85	1.1258
19	35	Biased-30krad	214.55	214.95	0.403
20	35	Biased-30krad	215.53	215.63	0.1039
30	50	Unbiased-50krad	208.65	209.66	1.0068
31	50	Unbiased-50krad	211.49	212.41	0.9173
32	50	Unbiased-50krad	222.79	221.05	-1.7401
33	50	Unbiased-50krad	215.59	215.37	-0.2201
34	50	Unbiased-50krad	216.57	216	-0.5741
40	55	Biased-50krad	218.86	221.78	2.9196
41	55	Biased-50krad	223.85	218.33	-5.5182
42	55	Biased-50krad	223.34	219.15	-4.1936
43	55	Biased-50krad	217.25	218.07	0.8237
44	55	Biased-50krad	218.37	219.33	0.9627
45	100	Unbiased-100krad	218.24	215.85	-2.3884
46	100	Unbiased-100krad	214.38	215.06	0.6731
47	100	Unbiased-100krad	220.15	218.63	-1.5183
48	100	Unbiased-100krad	217.6	215.8	-1.7975
49	100	Unbiased-100krad	223.6	221.4	-2.208
50	105	Biased-100krad	224.77	219.67	-5.1029
51	105	Biased-100krad	216.77	219.94	3.1692
52	105	Biased-100krad	215.67	214.84	-0.8258
53	105	Biased-100krad	222.14	216.91	-5.2286
54	105	Biased-100krad	218.17	221.11	2.9356

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	216.68	219.08	223.56	3.8812	217.3	219.58	223.48	3.3996	-0.0727	0.49723	0.943	0.51911
30	211.73	215.08	218.36	2.8067	211.66	216.77	219.17	3.0706	-0.07	1.6893	6.2097	2.5769
35	210.73	215.27	218.13	2.9153	211.85	215.77	218.47	2.642	0.1039	0.49484	1.1258	0.38193
50	208.65	215.02	222.79	5.3881	209.66	214.9	221.05	4.2702	-1.7401	-0.12204	1.0068	1.1387
55	217.25	220.33	223.85	3.0406	218.07	219.33	221.78	1.4655	-5.5182	-1.0012	2.9196	3.6454
100	214.38	218.79	223.6	3.3972	215.06	217.35	221.4	2.6423	-2.3884	-1.4478	0.6731	1.2337
105	215.67	219.5	224.77	3.8292	214.84	218.49	221.11	2.5565	-5.2286	-1.0105	3.1692	4.1114

Device Test: 72.17 _EXT_CLOCK|VIH/SYNC/3/3/////1.8///@SYNC_SW_VIH_VIN_3V





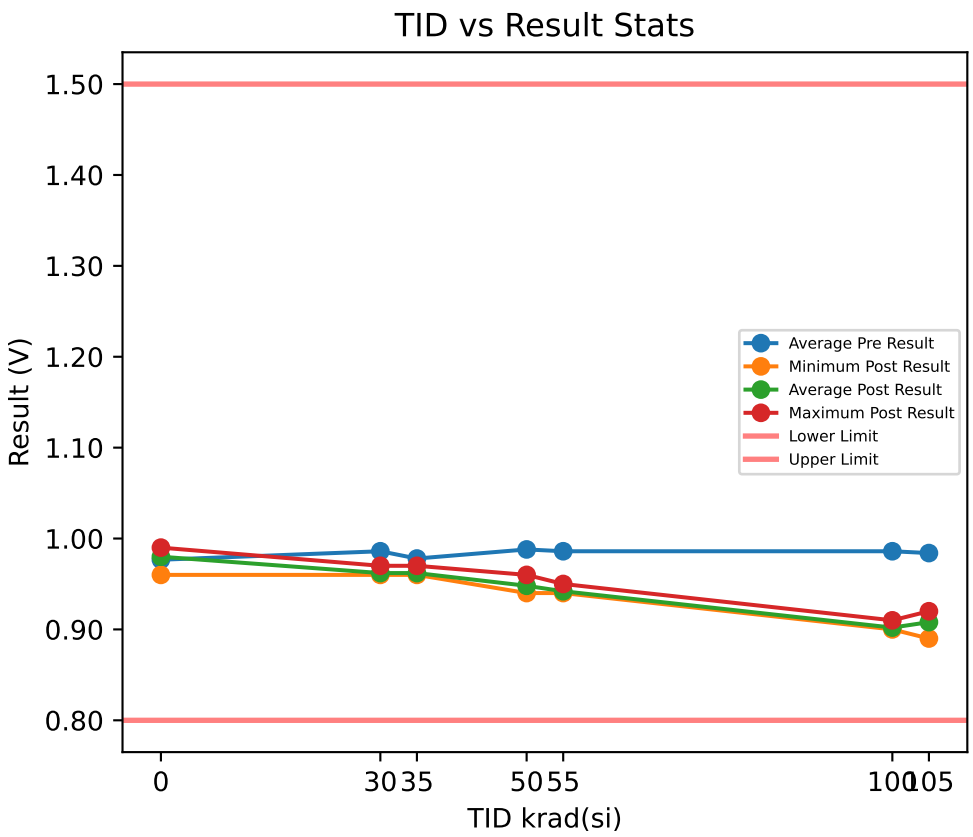
Test Results (Lower Limit = 0.5, Upper Limit = 1.4 (V))

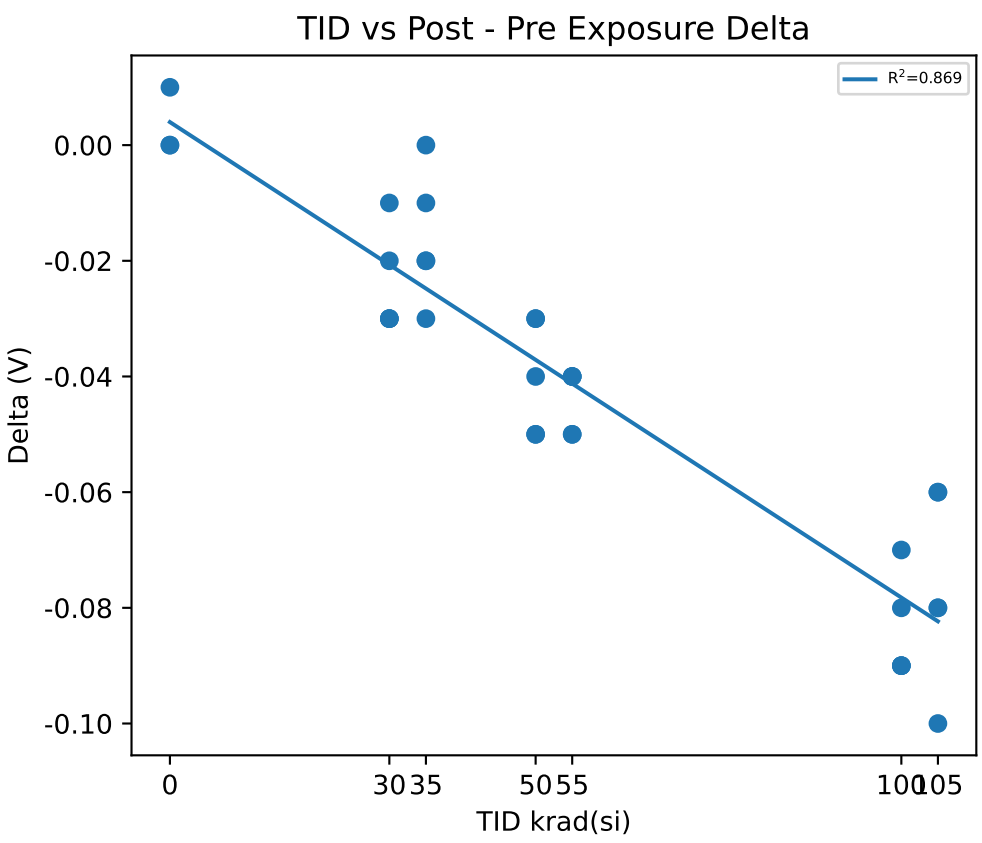
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.19	1.19	0
2	0	CU2	1.19	1.19	0
3	0	CU3	1.19	1.19	0
11	30	Unbiased-30krad	1.19	1.17	-0.02
12	30	Unbiased-30krad	1.18	1.16	-0.02
13	30	Unbiased-30krad	1.19	1.17	-0.02
14	30	Unbiased-30krad	1.19	1.17	-0.02
15	30	Unbiased-30krad	1.2	1.18	-0.02
16	35	Biased-30krad	1.18	1.16	-0.02
17	35	Biased-30krad	1.19	1.17	-0.02
18	35	Biased-30krad	1.18	1.16	-0.02
19	35	Biased-30krad	1.19	1.16	-0.03
20	35	Biased-30krad	1.2	1.17	-0.03
30	50	Unbiased-50krad	1.18	1.15	-0.03
31	50	Unbiased-50krad	1.2	1.16	-0.04
32	50	Unbiased-50krad	1.19	1.14	-0.05
33	50	Unbiased-50krad	1.19	1.15	-0.04
34	50	Unbiased-50krad	1.19	1.15	-0.04
40	55	Biased-50krad	1.19	1.15	-0.04
41	55	Biased-50krad	1.19	1.14	-0.05
42	55	Biased-50krad	1.18	1.13	-0.05
43	55	Biased-50krad	1.19	1.14	-0.05
44	55	Biased-50krad	1.19	1.13	-0.06
45	100	Unbiased-100krad	1.19	1.11	-0.08
46	100	Unbiased-100krad	1.19	1.11	-0.08
47	100	Unbiased-100krad	1.2	1.11	-0.09
48	100	Unbiased-100krad	1.19	1.11	-0.08
49	100	Unbiased-100krad	1.19	1.1	-0.09
50	105	Biased-100krad	1.19	1.12	-0.07
51	105	Biased-100krad	1.19	1.11	-0.08
52	105	Biased-100krad	1.18	1.1	-0.08
53	105	Biased-100krad	1.19	1.12	-0.07
54	105	Biased-100krad	1.19	1.11	-0.08

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.19	1.19	1.19	0	1.19	1.19	1.19	0	0	0	0	0
30	1.18	1.19	1.2	0.0070711	1.16	1.17	1.18	0.0070711	-0.02	-0.02	-0.02	0
35	1.18	1.188	1.2	0.0083666	1.16	1.164	1.17	0.0054772	-0.03	-0.024	-0.02	0.0054772
50	1.18	1.19	1.2	0.0070711	1.14	1.15	1.16	0.0070711	-0.05	-0.04	-0.03	0.0070711
55	1.18	1.188	1.19	0.0044721	1.13	1.138	1.15	0.0083666	-0.06	-0.05	-0.04	0.0070711
100	1.19	1.192	1.2	0.0044721	1.1	1.108	1.11	0.0044721	-0.09	-0.084	-0.08	0.0054772
105	1.18	1.188	1.19	0.0044721	1.1	1.112	1.12	0.0083666	-0.08	-0.076	-0.07	0.0054772

Device Test: 72.18 _EXT_CLOCK|VIL/SYNC/3/3/////1.8///@SYNC_VIL





Test Results (Lower Limit = 0.8, Upper Limit = 1.5 (V))

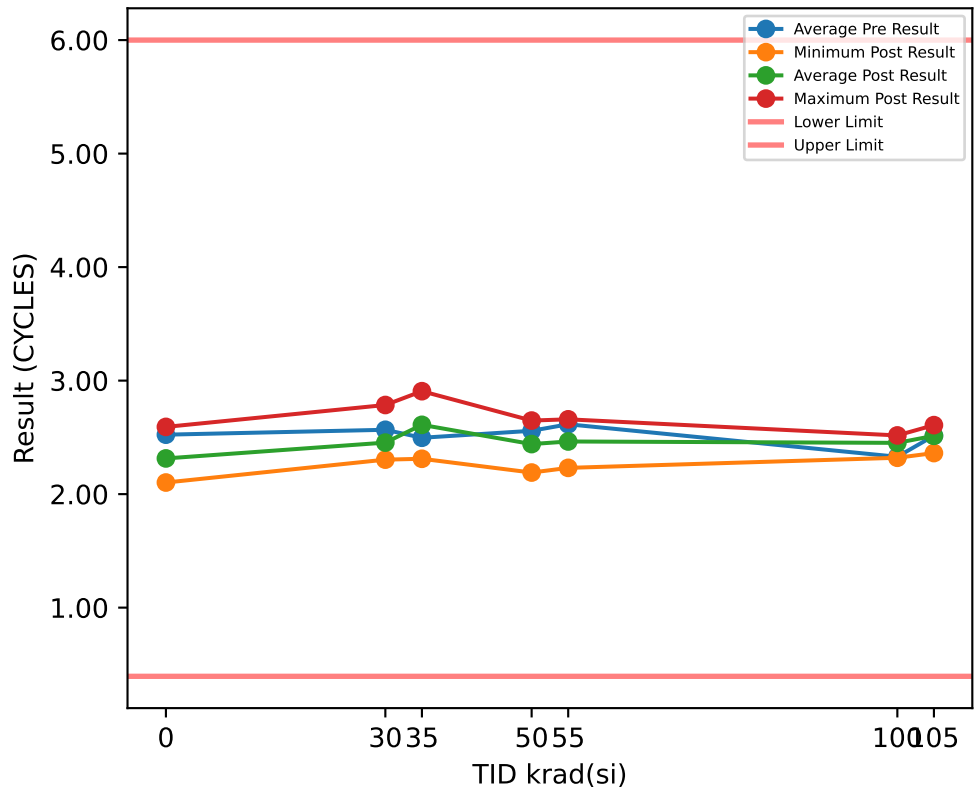
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.98	0.99	0.01
2	0	CU2	0.99	0.99	0
3	0	CU3	0.96	0.96	0
11	30	Unbiased-30krad	0.99	0.96	-0.03
12	30	Unbiased-30krad	0.97	0.96	-0.01
13	30	Unbiased-30krad	0.99	0.96	-0.03
14	30	Unbiased-30krad	0.99	0.96	-0.03
15	30	Unbiased-30krad	0.99	0.97	-0.02
16	35	Biased-30krad	0.96	0.96	0
17	35	Biased-30krad	0.98	0.96	-0.02
18	35	Biased-30krad	0.98	0.96	-0.02
19	35	Biased-30krad	0.99	0.96	-0.03
20	35	Biased-30krad	0.98	0.97	-0.01
30	50	Unbiased-50krad	0.98	0.95	-0.03
31	50	Unbiased-50krad	0.99	0.95	-0.04
32	50	Unbiased-50krad	0.99	0.94	-0.05
33	50	Unbiased-50krad	0.99	0.94	-0.05
34	50	Unbiased-50krad	0.99	0.96	-0.03
40	55	Biased-50krad	0.99	0.95	-0.04
41	55	Biased-50krad	0.99	0.94	-0.05
42	55	Biased-50krad	0.98	0.94	-0.04
43	55	Biased-50krad	0.99	0.94	-0.05
44	55	Biased-50krad	0.98	0.94	-0.04
45	100	Unbiased-100krad	0.98	0.9	-0.08
46	100	Unbiased-100krad	0.97	0.9	-0.07
47	100	Unbiased-100krad	1	0.91	-0.09
48	100	Unbiased-100krad	0.99	0.9	-0.09
49	100	Unbiased-100krad	0.99	0.9	-0.09
50	105	Biased-100krad	0.98	0.92	-0.06
51	105	Biased-100krad	0.98	0.9	-0.08
52	105	Biased-100krad	0.99	0.89	-0.1
53	105	Biased-100krad	0.99	0.91	-0.08
54	105	Biased-100krad	0.98	0.92	-0.06

Test Statistics (V)

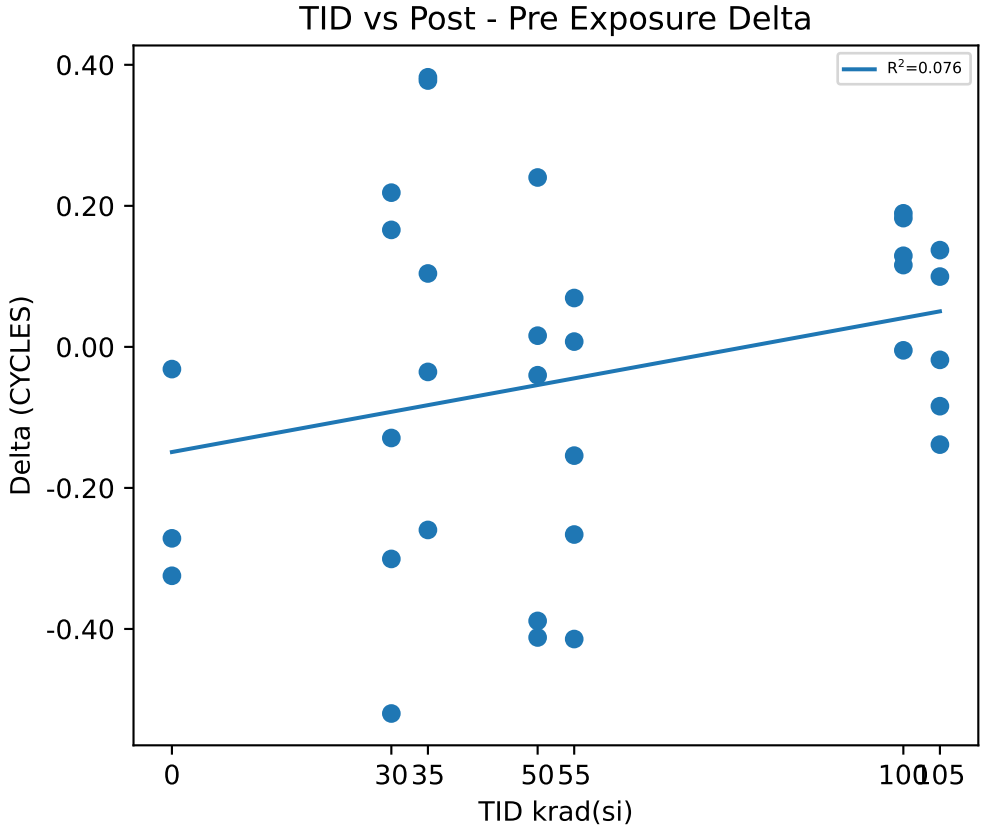
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.96	0.97667	0.99	0.015275	0.96	0.98	0.99	0.017321	0	0.0033333	0.01	0.0057735
30	0.97	0.986	0.99	0.0089443	0.96	0.962	0.97	0.0044721	-0.03	-0.024	-0.01	0.0089443
35	0.96	0.978	0.99	0.010954	0.96	0.962	0.97	0.0044721	-0.03	-0.016	0	0.011402
50	0.98	0.988	0.99	0.0044721	0.94	0.948	0.96	0.0083666	-0.05	-0.04	-0.03	0.01
55	0.98	0.986	0.99	0.0054772	0.94	0.942	0.95	0.0044721	-0.05	-0.044	-0.04	0.0054772
100	0.97	0.986	1	0.011402	0.9	0.902	0.91	0.0044721	-0.09	-0.084	-0.07	0.0089443
105	0.98	0.984	0.99	0.0054772	0.89	0.908	0.92	0.013038	-0.1	-0.076	-0.06	0.016733

Device Test: 72.22 _EXT_CLOCK|ExtToIntClkDetect/SW1/3/3/////1.8///@T_CLOCK_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



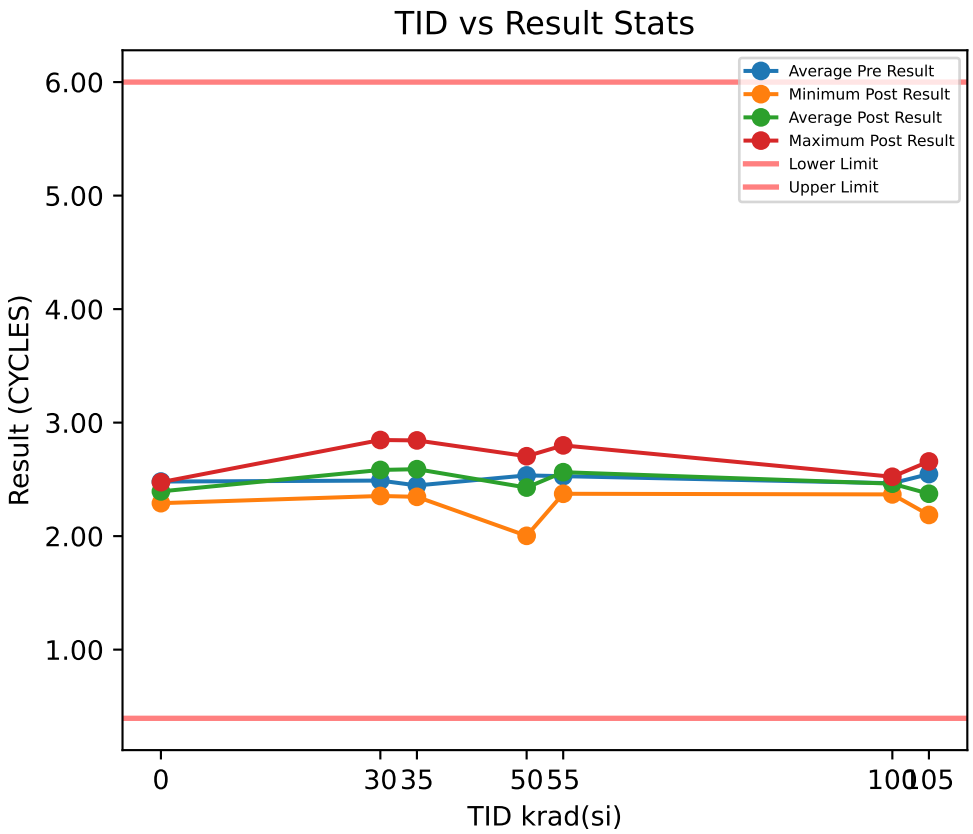
Test Results (Lower Limit = 0.395, Upper Limit = 6.0 (CYCLES))

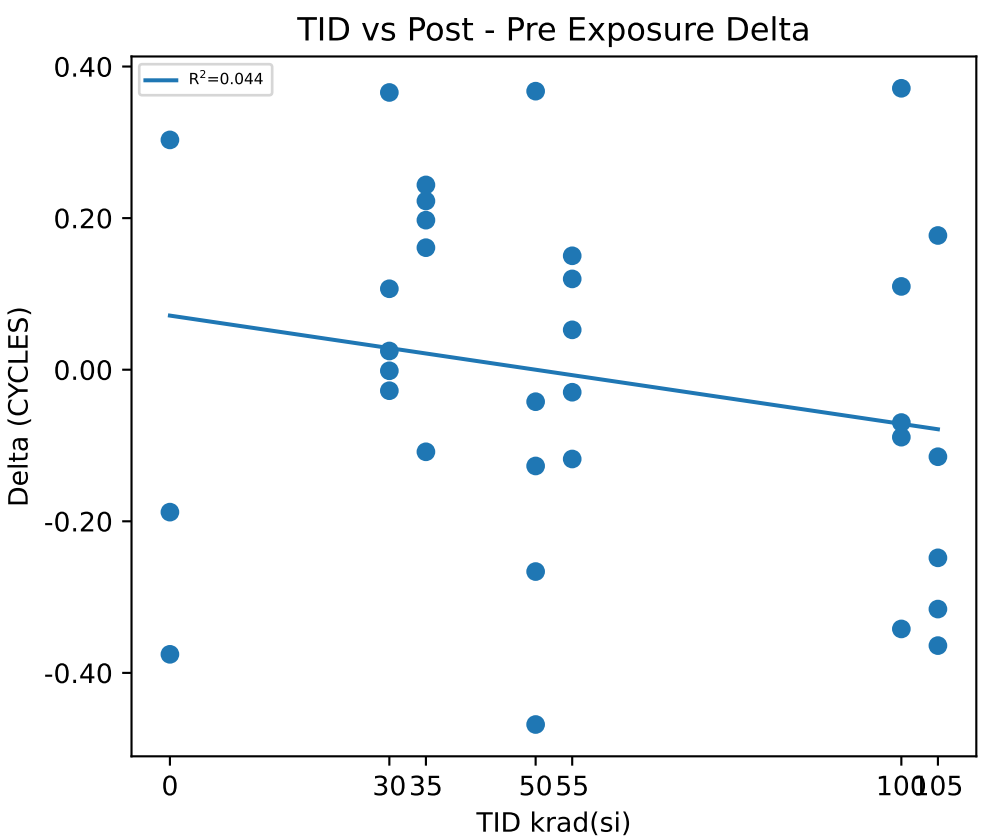
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3737	2.1022	-0.2715
2	0	CU2	2.5737	2.2491	-0.3246
3	0	CU3	2.6237	2.5922	-0.0315
11	30	Unbiased-30krad	2.6193	2.7852	0.1659
12	30	Unbiased-30krad	2.6678	2.3671	-0.3007
13	30	Unbiased-30krad	2.8237	2.3038	-0.5199
14	30	Unbiased-30krad	2.5769	2.4477	-0.1292
15	30	Unbiased-30krad	2.1466	2.3653	0.2187
16	35	Biased-30krad	2.5319	2.636	0.1041
17	35	Biased-30krad	2.5291	2.9068	0.3777
18	35	Biased-30krad	2.4468	2.8291	0.3823
19	35	Biased-30krad	2.5709	2.3113	-0.2596
20	35	Biased-30krad	2.4041	2.3686	-0.0355
30	50	Unbiased-50krad	2.444	2.4038	-0.0402
31	50	Unbiased-50krad	2.4079	2.6481	0.2402
32	50	Unbiased-50krad	2.8285	2.4164	-0.4121
33	50	Unbiased-50krad	2.5304	2.5463	0.0159
34	50	Unbiased-50krad	2.5787	2.1901	-0.3886
40	55	Biased-50krad	2.6515	2.659	0.0075
41	55	Biased-50krad	2.6908	2.4247	-0.2661
42	55	Biased-50krad	2.7729	2.3586	-0.4143
43	55	Biased-50krad	2.3855	2.2313	-0.1542
44	55	Biased-50krad	2.5759	2.6452	0.0693
45	100	Unbiased-100krad	2.3277	2.5171	0.1894
46	100	Unbiased-100krad	2.3845	2.5137	0.1292
47	100	Unbiased-100krad	2.3035	2.4861	0.1826
48	100	Unbiased-100krad	2.3049	2.4209	0.116
49	100	Unbiased-100krad	2.3252	2.3203	-0.0049
50	105	Biased-100krad	2.4459	2.3618	-0.0841
51	105	Biased-100krad	2.5454	2.527	-0.0184
52	105	Biased-100krad	2.4274	2.5271	0.0997
53	105	Biased-100krad	2.4081	2.5453	0.1372
54	105	Biased-100krad	2.7464	2.6078	-0.1386

Test Statistics (CYCLES)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3737	2.5237	2.6237	0.13229	2.1022	2.3145	2.5922	0.25146	-0.3246	-0.2092	-0.0315	0.15617
30	2.1466	2.5669	2.8237	0.2528	2.3038	2.4538	2.7852	0.19217	-0.5199	-0.11304	0.2187	0.3118
35	2.4041	2.4966	2.5709	0.068664	2.3113	2.6104	2.9068	0.26658	-0.2596	0.1138	0.3823	0.27548
50	2.4079	2.5579	2.8285	0.16575	2.1901	2.4409	2.6481	0.17242	-0.4121	-0.11696	0.2402	0.27929
55	2.3855	2.6153	2.7729	0.14681	2.2313	2.4638	2.659	0.18551	-0.4143	-0.15156	0.0693	0.19763
100	2.3035	2.3292	2.3845	0.032891	2.3203	2.4516	2.5171	0.082944	-0.0049	0.12246	0.1894	0.078111
105	2.4081	2.5146	2.7464	0.13995	2.3618	2.5138	2.6078	0.091219	-0.1386	-0.00084	0.1372	0.11767

Device Test: 72.23 _EXT_CLOCK|ExtToIntClkDetect/SW2/3/3/////1.8///@T_CLOCK_DET





Test Results (Lower Limit = 0.395, Upper Limit = 6.0 (CYCLES))

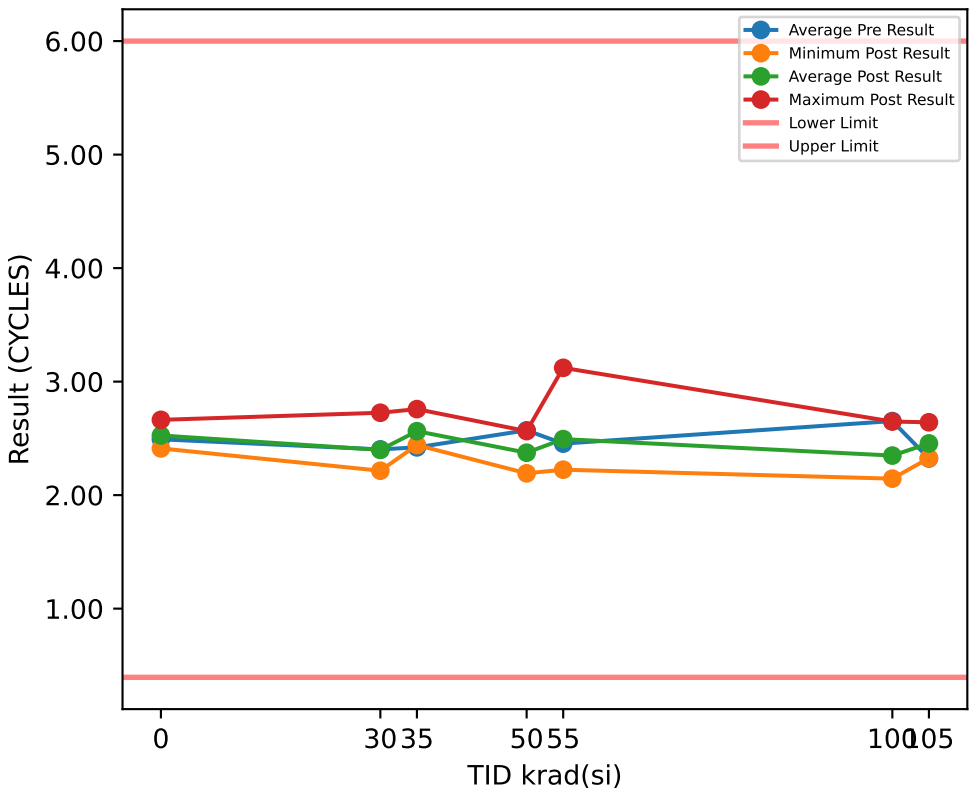
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.6658	2.2903	-0.3755
2	0	CU2	2.6048	2.4169	-0.1879
3	0	CU3	2.1719	2.4751	0.3032
11	30	Unbiased-30krad	2.5275	2.6343	0.1068
12	30	Unbiased-30krad	2.3814	2.3537	-0.0277
13	30	Unbiased-30krad	2.5472	2.5719	0.0247
14	30	Unbiased-30krad	2.5095	2.5081	-0.0014
15	30	Unbiased-30krad	2.481	2.8468	0.3658
16	35	Biased-30krad	2.3793	2.5766	0.1973
17	35	Biased-30krad	2.6206	2.8432	0.2226
18	35	Biased-30krad	2.1852	2.3462	0.161
19	35	Biased-30krad	2.4908	2.7346	0.2438
20	35	Biased-30krad	2.5566	2.4483	-0.1083
30	50	Unbiased-50krad	2.6113	2.5691	-0.0422
31	50	Unbiased-50krad	2.6389	2.5119	-0.127
32	50	Unbiased-50krad	2.4707	2.0026	-0.4681
33	50	Unbiased-50krad	2.6177	2.3514	-0.2663
34	50	Unbiased-50krad	2.3363	2.7038	0.3675
40	55	Biased-50krad	2.6975	2.5797	-0.1178
41	55	Biased-50krad	2.3205	2.3731	0.0526
42	55	Biased-50krad	2.8292	2.7995	-0.0297
43	55	Biased-50krad	2.2582	2.4085	0.1503
44	55	Biased-50krad	2.5355	2.6553	0.1198
45	100	Unbiased-100krad	2.4793	2.3903	-0.089
46	100	Unbiased-100krad	2.1516	2.5229	0.3713
47	100	Unbiased-100krad	2.7096	2.3676	-0.342
48	100	Unbiased-100krad	2.4019	2.5118	0.1099
49	100	Unbiased-100krad	2.5871	2.5174	-0.0697
50	105	Biased-100krad	2.7081	2.3923	-0.3158
51	105	Biased-100krad	2.5644	2.2004	-0.364
52	105	Biased-100krad	2.3013	2.1865	-0.1148
53	105	Biased-100krad	2.6786	2.4304	-0.2482
54	105	Biased-100krad	2.4808	2.6579	0.1771

Test Statistics (CYCLES)

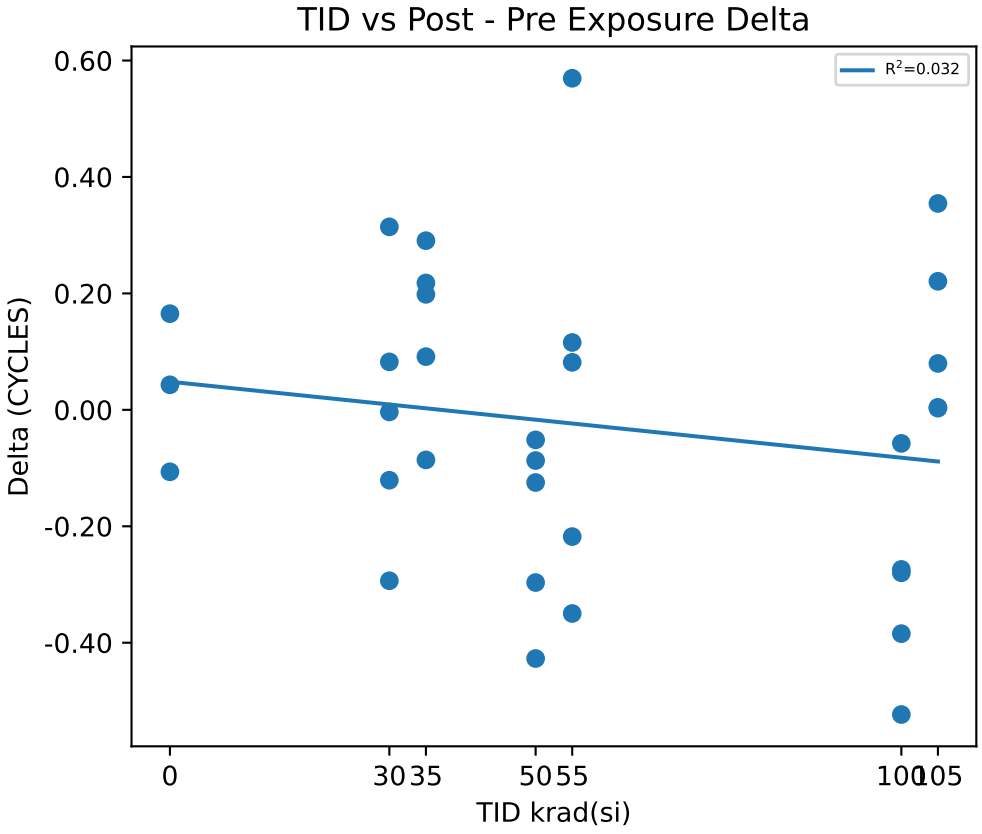
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1719	2.4808	2.6658	0.26928	2.2903	2.3941	2.4751	0.094486	-0.3755	-0.086733	0.3032	0.35048
30	2.3814	2.4893	2.5472	0.06506	2.3537	2.583	2.8468	0.18065	-0.0277	0.09364	0.3658	0.16028
35	2.1852	2.4465	2.6206	0.17116	2.3462	2.5898	2.8432	0.20293	-0.1083	0.14328	0.2438	0.14398
50	2.3363	2.535	2.6389	0.12949	2.0026	2.4278	2.7038	0.26919	-0.4681	-0.10722	0.3675	0.31045
55	2.2582	2.5282	2.8292	0.24257	2.3731	2.5632	2.7995	0.17654	-0.1178	0.03504	0.1503	0.10992
100	2.1516	2.4659	2.7096	0.21044	2.3676	2.462	2.5229	0.076338	-0.342	-0.0039	0.3713	0.26439
105	2.3013	2.5466	2.7081	0.16456	2.1865	2.3735	2.6579	0.19327	-0.364	-0.17314	0.1771	0.21707

Device Test: 72.24 _EXT_CLOCK|ExtToIntClkDetect/SW3/3/3/////1.8///@T_CLOCK_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



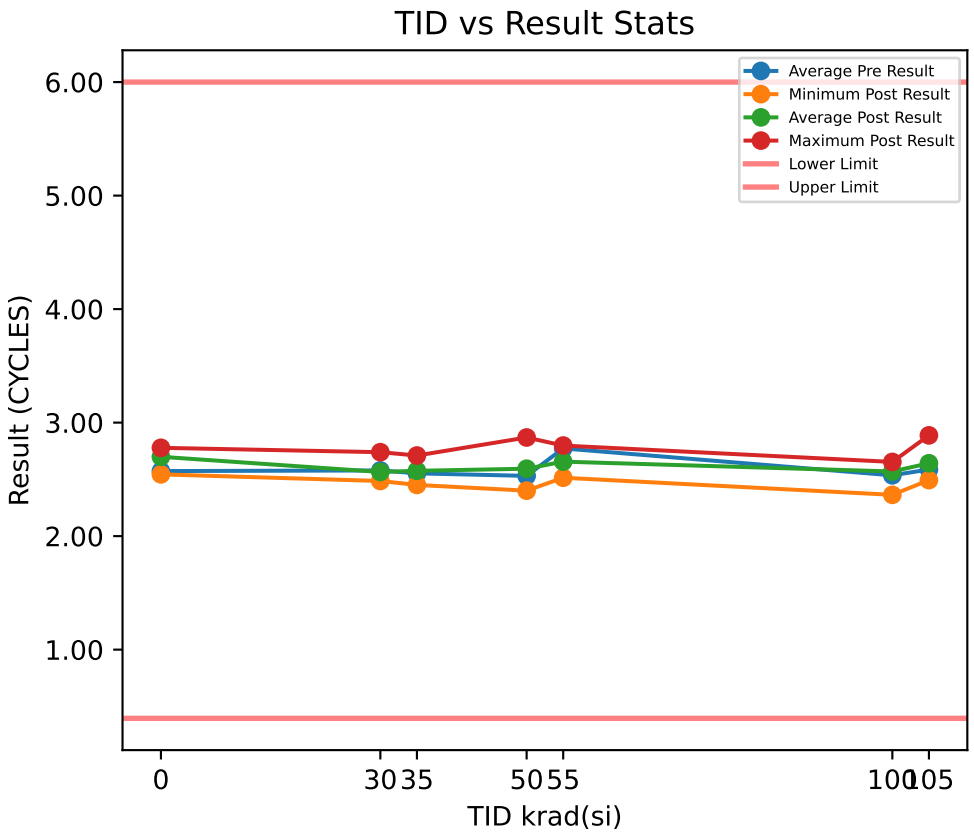
Test Results (Lower Limit = 0.395, Upper Limit = 6.0 (CYCLES))

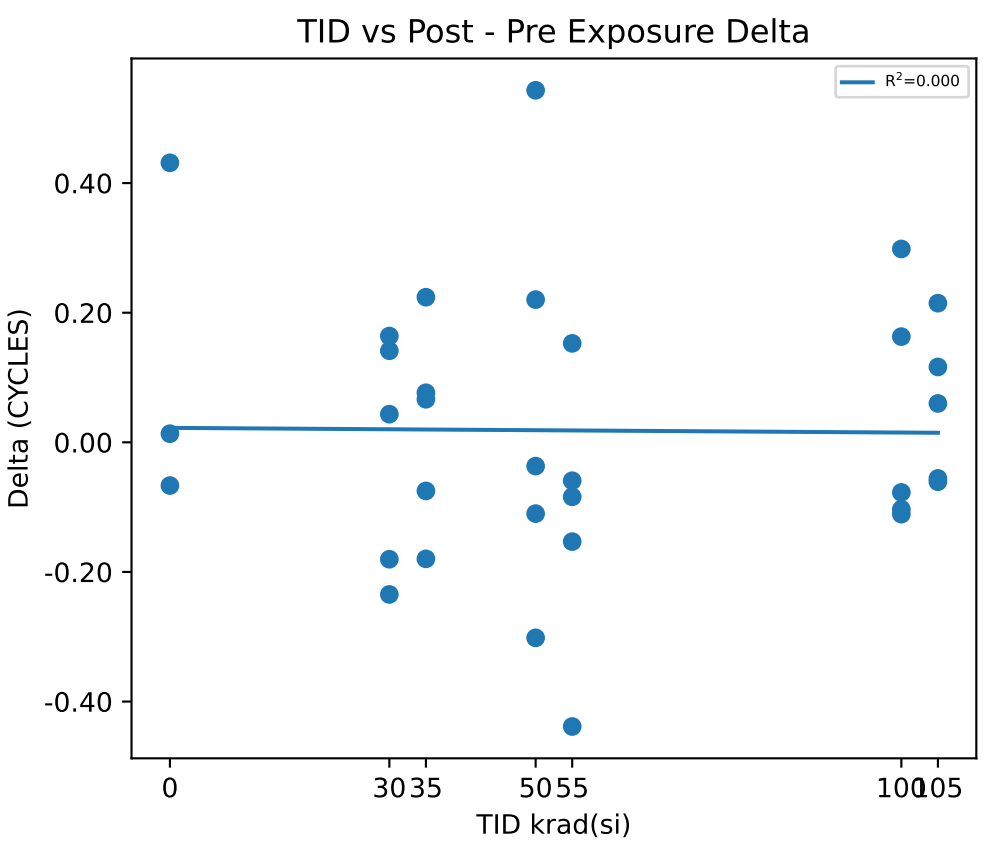
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4979	2.6631	0.1652
2	0	CU2	2.4592	2.5022	0.043
3	0	CU3	2.518	2.4116	-0.1064
11	30	Unbiased-30krad	2.1658	2.4801	0.3143
12	30	Unbiased-30krad	2.2918	2.2882	-0.0036
13	30	Unbiased-30krad	2.6433	2.7257	0.0824
14	30	Unbiased-30krad	2.5772	2.2836	-0.2936
15	30	Unbiased-30krad	2.3358	2.2149	-0.1209
16	35	Biased-30krad	2.5398	2.7577	0.2179
17	35	Biased-30krad	2.2751	2.5657	0.2906
18	35	Biased-30krad	2.3746	2.573	0.1984
19	35	Biased-30krad	2.5271	2.4411	-0.086
20	35	Biased-30krad	2.3879	2.4793	0.0914
30	50	Unbiased-50krad	2.6193	2.1922	-0.4271
31	50	Unbiased-50krad	2.5343	2.2377	-0.2966
32	50	Unbiased-50krad	2.6156	2.564	-0.0516
33	50	Unbiased-50krad	2.4385	2.3137	-0.1248
34	50	Unbiased-50krad	2.648	2.5609	-0.0871
40	55	Biased-50krad	2.547	2.6286	0.0816
41	55	Biased-50krad	2.4418	2.2241	-0.2177
42	55	Biased-50krad	2.153	2.2687	0.1157
43	55	Biased-50krad	2.5519	3.1214	0.5695
44	55	Biased-50krad	2.5747	2.2249	-0.3498
45	100	Unbiased-100krad	2.5491	2.4915	-0.0576
46	100	Unbiased-100krad	2.9222	2.6481	-0.2741
47	100	Unbiased-100krad	2.6685	2.1452	-0.5233
48	100	Unbiased-100krad	2.6301	2.2457	-0.3844
49	100	Unbiased-100krad	2.4918	2.2119	-0.2799
50	105	Biased-100krad	2.353	2.3559	0.0029
51	105	Biased-100krad	2.3385	2.5593	0.2208
52	105	Biased-100krad	2.2461	2.3258	0.0797
53	105	Biased-100krad	2.3903	2.3946	0.0043
54	105	Biased-100krad	2.2872	2.6417	0.3545

Test Statistics (CYCLES)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4592	2.4917	2.518	0.029886	2.4116	2.5256	2.6631	0.12738	-0.1064	0.033933	0.1652	0.13603
30	2.1658	2.4028	2.6433	0.20077	2.2149	2.3985	2.7257	0.20784	-0.2936	-0.00428	0.3143	0.22711
35	2.2751	2.4209	2.5398	0.1117	2.4411	2.5634	2.7577	0.12235	-0.086	0.14246	0.2906	0.14626
50	2.4385	2.5711	2.648	0.085373	2.1922	2.3737	2.564	0.17769	-0.4271	-0.19744	-0.0516	0.15914
55	2.153	2.4537	2.5747	0.17575	2.2241	2.4935	3.1214	0.3898	-0.3498	0.03986	0.5695	0.35573
100	2.4918	2.6523	2.9222	0.16584	2.1452	2.3485	2.6481	0.21258	-0.5233	-0.30386	-0.0576	0.17084
105	2.2461	2.323	2.3903	0.056712	2.3258	2.4555	2.6417	0.13775	0.0029	0.13244	0.3545	0.15256

Device Test: 72.25 _EXT_CLOCK|ExtToIntClkDetect/SW4/3/3/////1.8///@T_CLOCK_DET





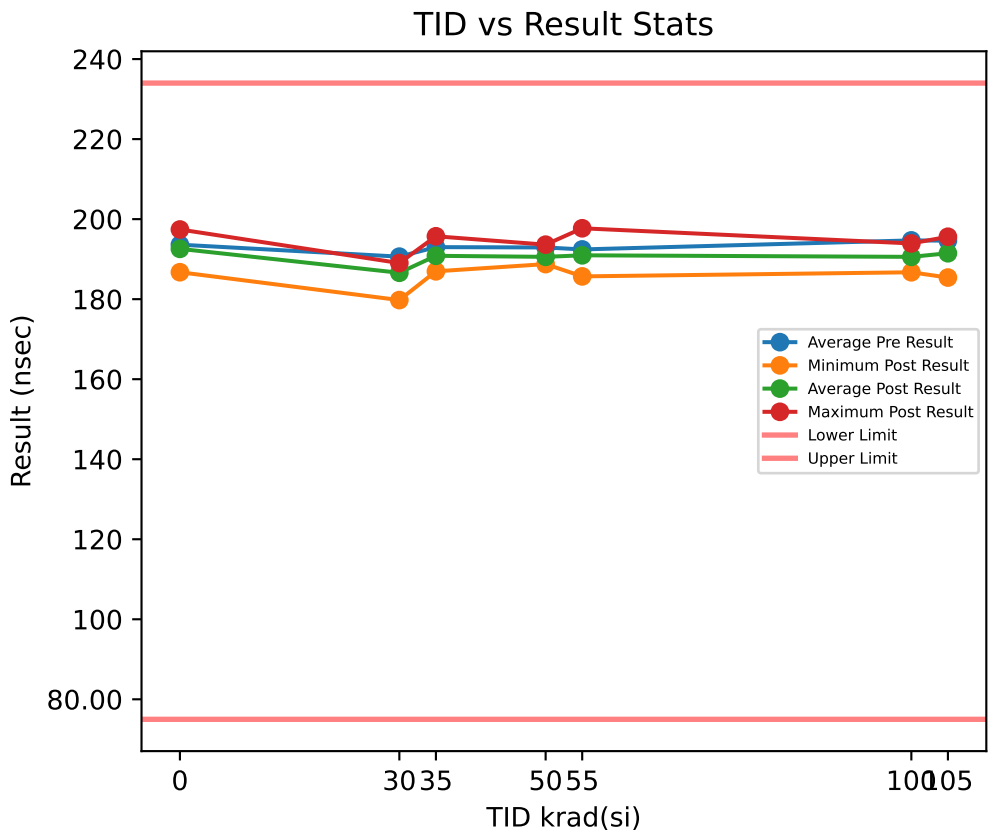
Test Results (Lower Limit = 0.395, Upper Limit = 6.0 (CYCLES))

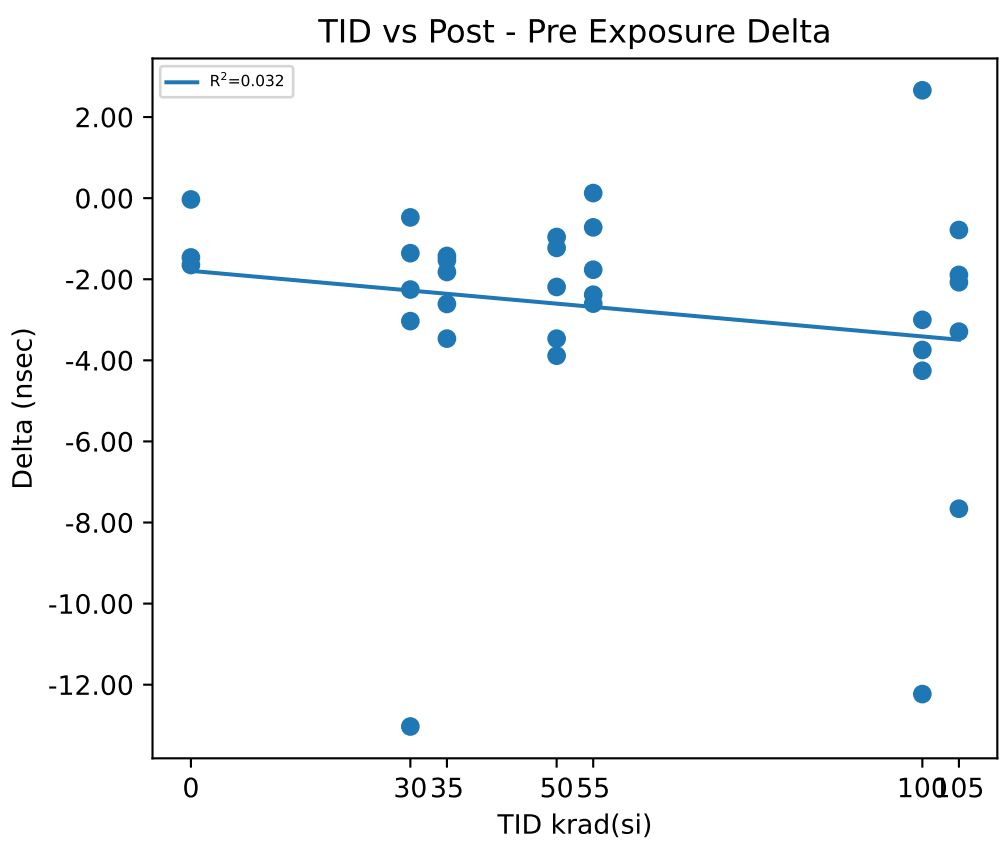
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.8447	2.778	-0.0667
2	0	CU2	2.7614	2.7747	0.0133
3	0	CU3	2.113	2.5443	0.4313
11	30	Unbiased-30krad	2.4423	2.4857	0.0434
12	30	Unbiased-30krad	2.6897	2.5093	-0.1804
13	30	Unbiased-30krad	2.5755	2.7395	0.164
14	30	Unbiased-30krad	2.748	2.5133	-0.2347
15	30	Unbiased-30krad	2.4378	2.5791	0.1413
16	35	Biased-30krad	2.2654	2.4893	0.2239
17	35	Biased-30krad	2.6336	2.7101	0.0765
18	35	Biased-30krad	2.6098	2.6762	0.0664
19	35	Biased-30krad	2.6255	2.5505	-0.075
20	35	Biased-30krad	2.6308	2.451	-0.1798
30	50	Unbiased-50krad	2.4389	2.6591	0.2202
31	50	Unbiased-50krad	2.4371	2.4004	-0.0367
32	50	Unbiased-50krad	2.3258	2.869	0.5432
33	50	Unbiased-50krad	2.5955	2.4855	-0.11
34	50	Unbiased-50krad	2.8568	2.5551	-0.3017
40	55	Biased-50krad	2.7777	2.7185	-0.0592
41	55	Biased-50krad	2.9511	2.7979	-0.1532
42	55	Biased-50krad	2.3619	2.5146	0.1527
43	55	Biased-50krad	2.7205	2.6364	-0.0841
44	55	Biased-50krad	3.0521	2.6136	-0.4385
45	100	Unbiased-100krad	2.7511	2.6478	-0.1033
46	100	Unbiased-100krad	2.6981	2.5873	-0.1108
47	100	Unbiased-100krad	2.4905	2.6536	0.1631
48	100	Unbiased-100krad	2.4411	2.3638	-0.0773
49	100	Unbiased-100krad	2.2972	2.5956	0.2984
50	105	Biased-100krad	2.4453	2.5616	0.1163
51	105	Biased-100krad	2.673	2.8877	0.2147
52	105	Biased-100krad	2.5814	2.6414	0.06
53	105	Biased-100krad	2.6864	2.6256	-0.0608
54	105	Biased-100krad	2.5491	2.4934	-0.0557

Test Statistics (CYCLES)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.113	2.573	2.8447	0.40057	2.5443	2.699	2.778	0.13398	-0.0667	0.12597	0.4313	0.26743
30	2.4378	2.5787	2.748	0.14094	2.4857	2.5654	2.7395	0.10333	-0.2347	-0.01328	0.164	0.18405
35	2.2654	2.553	2.6336	0.16105	2.451	2.5754	2.7101	0.11381	-0.1798	0.0224	0.2239	0.15479
50	2.3258	2.5308	2.8568	0.20598	2.4004	2.5938	2.869	0.18071	-0.3017	0.063	0.5432	0.32718
55	2.3619	2.7727	3.0521	0.26523	2.5146	2.6562	2.7979	0.10749	-0.4385	-0.11646	0.1527	0.21321
100	2.2972	2.5356	2.7511	0.18751	2.3638	2.5696	2.6536	0.11886	-0.1108	0.03402	0.2984	0.18627
105	2.4453	2.587	2.6864	0.098518	2.4934	2.6419	2.8877	0.14932	-0.0608	0.0549	0.2147	0.11721

Device Test: 73.1 _EXT_CLOCK|Delay/SYNC_to_SW1/5/5/////1.8///@SYNC_SW_DELAY_VIN_5V





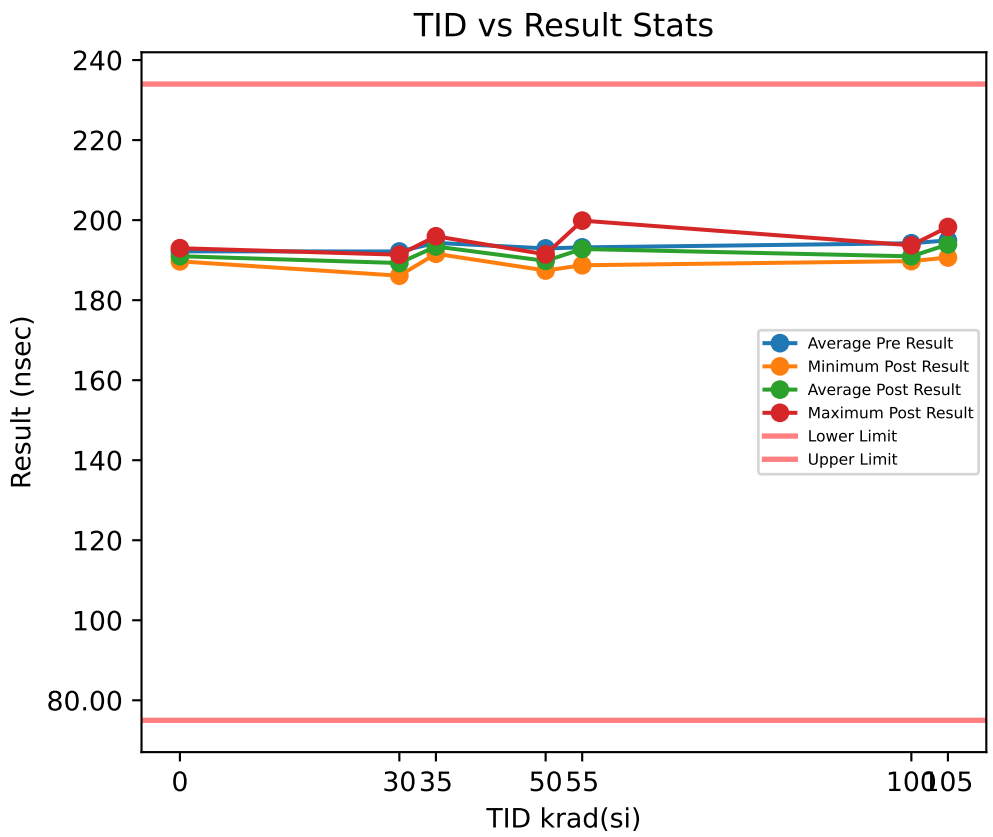
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

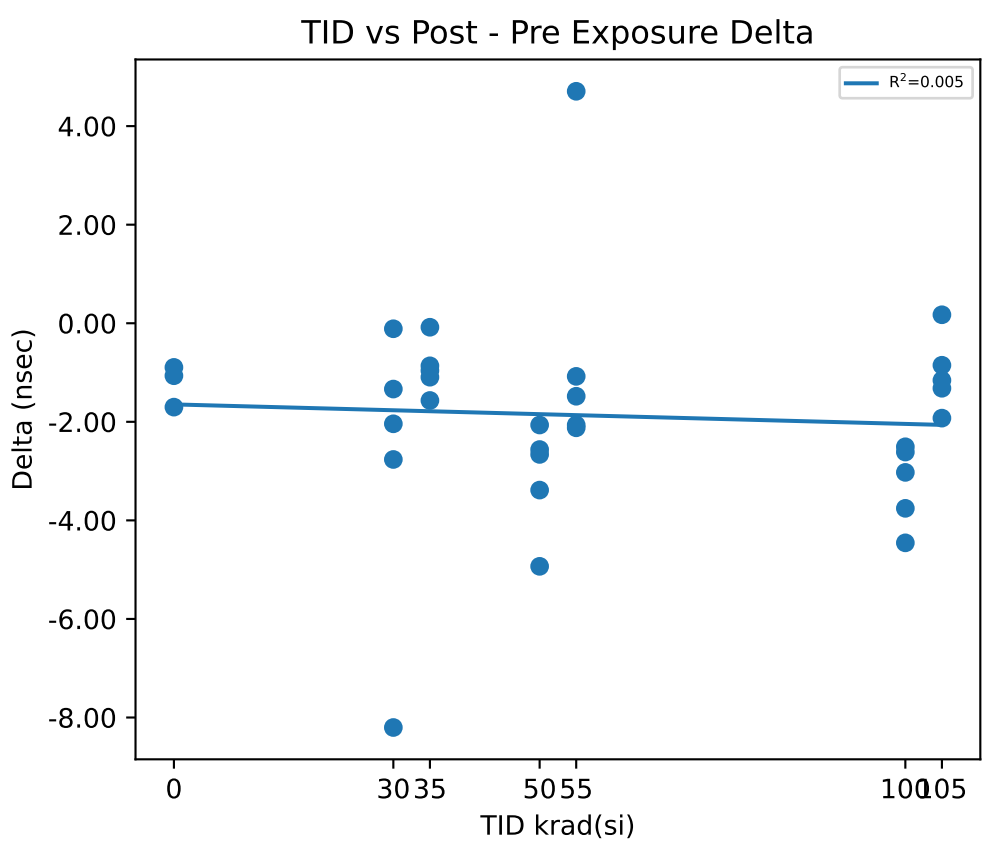
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	188.38	186.73	-1.6492
2	0	CU2	197.45	197.41	-0.0326
3	0	CU3	195.03	193.57	-1.4625
11	30	Unbiased-30krad	188.48	187.12	-1.3573
12	30	Unbiased-30krad	191.92	188.88	-3.0328
13	30	Unbiased-30krad	189.5	189.03	-0.4751
14	30	Unbiased-30krad	190.43	188.18	-2.2545
15	30	Unbiased-30krad	192.8	179.77	-13.031
16	35	Biased-30krad	190.42	186.96	-3.4642
17	35	Biased-30krad	189.99	188.56	-1.4259
18	35	Biased-30krad	197.54	195.71	-1.821
19	35	Biased-30krad	191.05	189.52	-1.5318
20	35	Biased-30krad	196.03	193.42	-2.6096
30	50	Unbiased-50krad	190.02	189.07	-0.9588
31	50	Unbiased-50krad	193.35	191.16	-2.1907
32	50	Unbiased-50krad	197.08	193.62	-3.4652
33	50	Unbiased-50krad	194.16	190.27	-3.8854
34	50	Unbiased-50krad	189.99	188.76	-1.2266
40	55	Biased-50krad	189.78	187.18	-2.6016
41	55	Biased-50krad	188.07	185.69	-2.3816
42	55	Biased-50krad	189.87	189.15	-0.7206
43	55	Biased-50krad	196.82	195.05	-1.7652
44	55	Biased-50krad	197.59	197.71	0.1253
45	100	Unbiased-100krad	197.67	193.93	-3.7446
46	100	Unbiased-100krad	194.97	191.97	-3.0015
47	100	Unbiased-100krad	190.15	192.81	2.6603
48	100	Unbiased-100krad	191.7	187.44	-4.2562
49	100	Unbiased-100krad	198.95	186.72	-12.231
50	105	Biased-100krad	186.19	185.4	-0.7855
51	105	Biased-100krad	198.89	195.6	-3.2927
52	105	Biased-100krad	194.87	187.21	-7.6599
53	105	Biased-100krad	197.54	195.46	-2.0744
54	105	Biased-100krad	195.6	193.71	-1.8932

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.38	193.62	197.45	4.695	186.73	192.57	197.41	5.4108	-1.6492	-1.0481	-0.0326	0.88439
30	188.48	190.63	192.8	1.7557	179.77	186.6	189.03	3.8881	-13.031	-4.0302	-0.4751	5.1222
35	189.99	193	197.54	3.5086	186.96	190.83	195.71	3.6194	-3.4642	-2.1705	-1.4259	0.85892
50	189.99	192.92	197.08	3.0015	188.76	190.58	193.62	1.9539	-3.8854	-2.3453	-0.9588	1.3061
55	188.07	192.43	197.59	4.4274	185.69	190.96	197.71	5.1887	-2.6016	-1.4687	0.1253	1.1517
100	190.15	194.69	198.95	3.7649	186.72	190.57	193.93	3.2741	-12.231	-4.1146	2.6603	5.3192
105	186.19	194.62	198.89	4.9726	185.4	191.48	195.6	4.8212	-7.6599	-3.1411	-0.7855	2.678

Device Test: 73.2 _EXT_CLOCK|Delay/SYNC_to_SW2/5/5/////1.8///@SYNC_SW_DELAY_VIN_5V





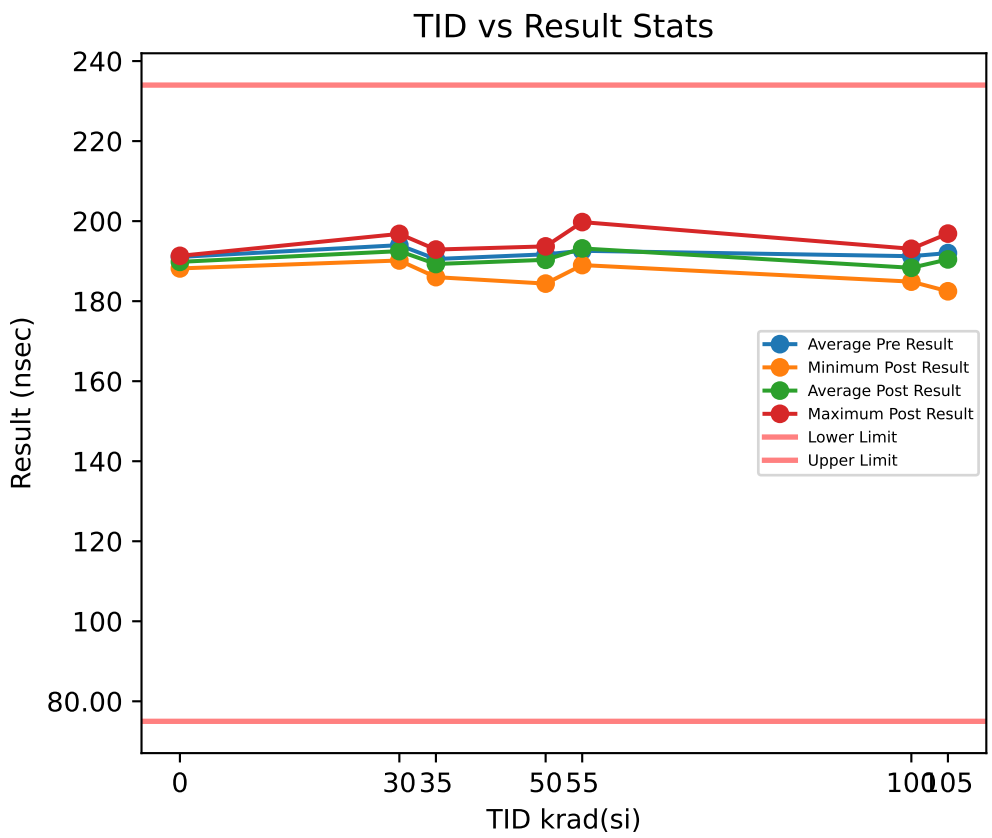
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

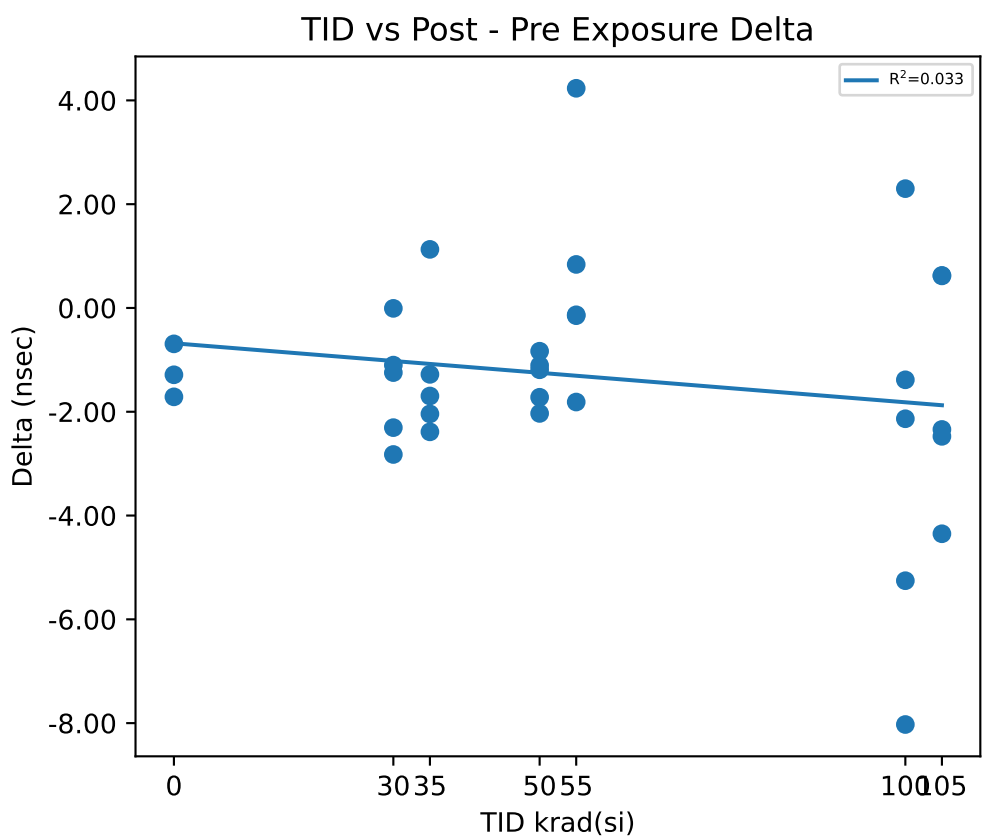
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	194.69	192.99	-1.702
2	0	CU2	190.6	189.7	-0.8957
3	0	CU3	191.33	190.26	-1.0646
11	30	Unbiased-30krad	190.2	187.44	-2.764
12	30	Unbiased-30krad	194.31	186.11	-8.2028
13	30	Unbiased-30krad	192.21	190.17	-2.0404
14	30	Unbiased-30krad	192.63	191.29	-1.3352
15	30	Unbiased-30krad	191.47	191.36	-0.1119
16	35	Biased-30krad	191.68	191.59	-0.081
17	35	Biased-30krad	194.57	193.62	-0.959
18	35	Biased-30krad	197.53	195.97	-1.567
19	35	Biased-30krad	193.47	192.61	-0.8639
20	35	Biased-30krad	194.35	193.25	-1.0946
30	50	Unbiased-50krad	190.07	187.41	-2.6616
31	50	Unbiased-50krad	194	191.44	-2.5624
32	50	Unbiased-50krad	194.42	189.49	-4.9325
33	50	Unbiased-50krad	194.4	191.01	-3.3853
34	50	Unbiased-50krad	191.78	189.71	-2.0646
40	55	Biased-50krad	195.17	199.88	4.7067
41	55	Biased-50krad	190.84	188.72	-2.1215
42	55	Biased-50krad	191.79	189.73	-2.0634
43	55	Biased-50krad	194.33	192.85	-1.4812
44	55	Biased-50krad	193.81	192.74	-1.0779
45	100	Unbiased-100krad	192.26	189.75	-2.5066
46	100	Unbiased-100krad	194.48	190.72	-3.7556
47	100	Unbiased-100krad	196.74	193.71	-3.0262
48	100	Unbiased-100krad	192.56	189.94	-2.6136
49	100	Unbiased-100krad	195.08	190.62	-4.4558
50	105	Biased-100krad	190.48	190.66	0.1722
51	105	Biased-100krad	194.62	192.7	-1.9252
52	105	Biased-100krad	195.9	194.74	-1.1574
53	105	Biased-100krad	199.14	198.28	-0.8523
54	105	Biased-100krad	194.58	193.26	-1.3192

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	190.6	192.21	194.69	2.181	189.7	190.98	192.99	1.756	-1.702	-1.2208	-0.8957	0.42523
30	190.2	192.17	194.31	1.5139	186.11	189.27	191.36	2.3766	-8.2028	-2.8909	-0.1119	3.1265
35	191.68	194.32	197.53	2.1282	191.59	193.41	195.97	1.6242	-1.567	-0.9131	-0.081	0.53792
50	190.07	192.93	194.42	1.9402	187.41	189.81	191.44	1.5813	-4.9325	-3.1213	-2.0646	1.117
55	190.84	193.19	195.17	1.8079	188.72	192.78	199.88	4.3639	-2.1215	-0.40746	4.7067	2.8912
100	192.26	194.22	196.74	1.8538	189.75	190.95	193.71	1.599	-4.4558	-3.2716	-2.5066	0.82386
105	190.48	194.94	199.14	3.1069	190.66	193.93	198.28	2.8417	-1.9252	-1.0164	0.1722	0.77091

Device Test: 73.3 _EXT_CLOCK|Delay/SYNC_to_SW3/5/5/////1.8///@SYNC_SW_DELAY_VIN_5V





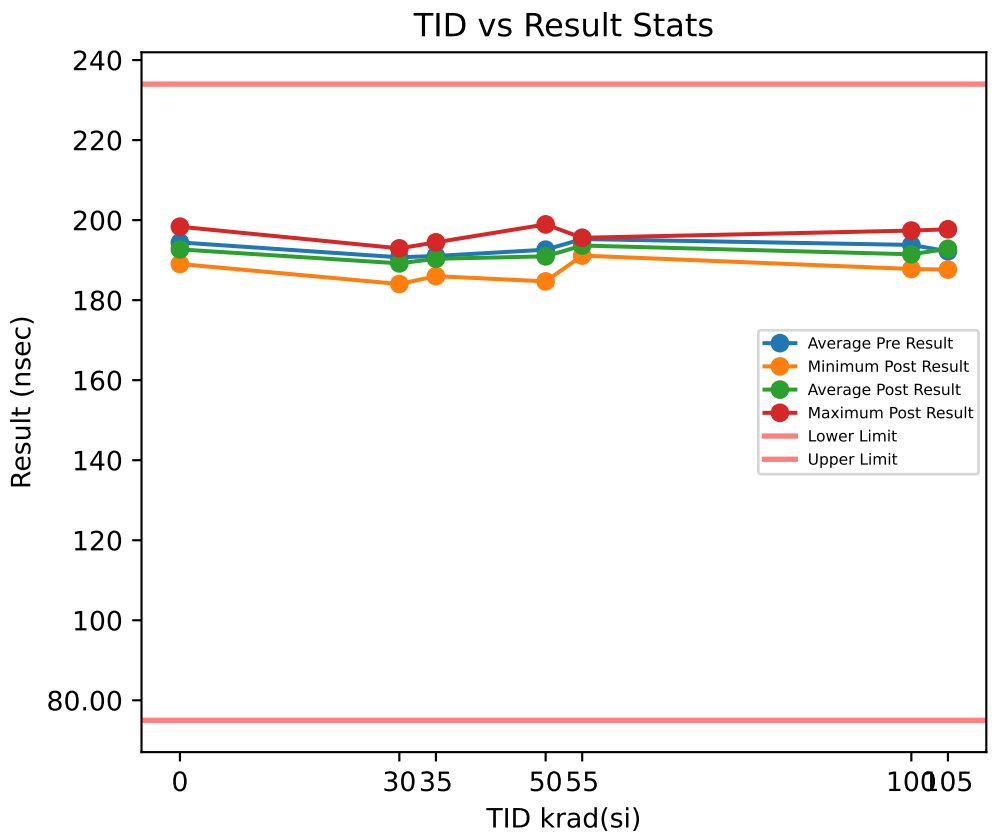
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

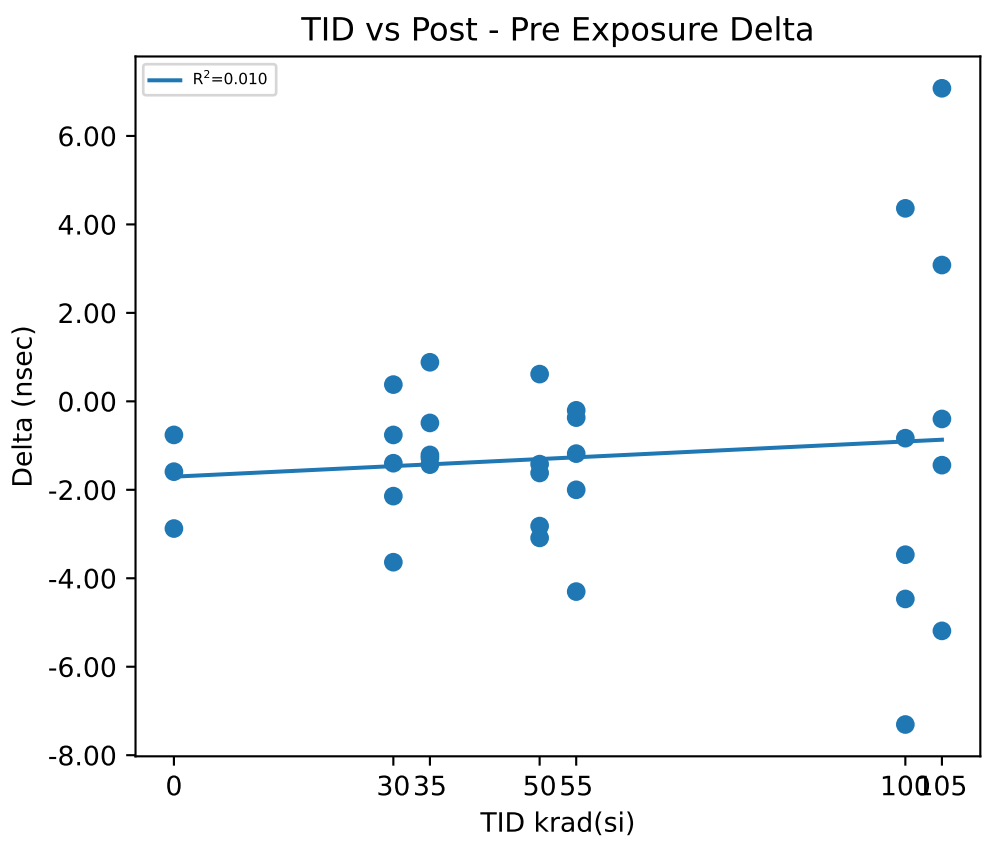
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	191.67	189.96	-1.7127
2	0	CU2	192.61	191.32	-1.2876
3	0	CU3	188.87	188.18	-0.6917
11	30	Unbiased-30krad	190.17	190.17	-0.0076
12	30	Unbiased-30krad	192.36	191.11	-1.2453
13	30	Unbiased-30krad	195.89	193.58	-2.3059
14	30	Unbiased-30krad	193.65	190.83	-2.8233
15	30	Unbiased-30krad	197.91	196.81	-1.1011
16	35	Biased-30krad	193.16	191.88	-1.2794
17	35	Biased-30krad	195.29	192.9	-2.387
18	35	Biased-30krad	186.23	187.36	1.1291
19	35	Biased-30krad	190.3	188.26	-2.0415
20	35	Biased-30krad	187.7	186	-1.6963
30	50	Unbiased-50krad	185.58	184.39	-1.1909
31	50	Unbiased-50krad	193.62	191.9	-1.7206
32	50	Unbiased-50krad	193.53	191.5	-2.0321
33	50	Unbiased-50krad	191.3	190.2	-1.1061
34	50	Unbiased-50krad	194.52	193.69	-0.8334
40	55	Biased-50krad	191.19	195.42	4.2332
41	55	Biased-50krad	192.08	190.27	-1.8125
42	55	Biased-50krad	191.57	191.43	-0.1314
43	55	Biased-50krad	188.18	189.02	0.839
44	55	Biased-50krad	199.91	199.76	-0.1486
45	100	Unbiased-100krad	195.16	189.9	-5.2555
46	100	Unbiased-100krad	192.91	184.88	-8.0266
47	100	Unbiased-100krad	190.79	193.09	2.2995
48	100	Unbiased-100krad	187.11	184.97	-2.1348
49	100	Unbiased-100krad	190.24	188.86	-1.3842
50	105	Biased-100krad	193.56	189.2	-4.3509
51	105	Biased-100krad	190.46	191.08	0.6274
52	105	Biased-100krad	184.81	182.47	-2.3409
53	105	Biased-100krad	196.26	196.88	0.6182
54	105	Biased-100krad	195.01	192.54	-2.4737

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.87	191.05	192.61	1.9445	188.18	189.82	191.32	1.5753	-1.7127	-1.2307	-0.6917	0.51288
30	190.17	194	197.91	3.0146	190.17	192.5	196.81	2.7357	-2.8233	-1.4966	-0.0076	1.1013
35	186.23	190.54	195.29	3.744	186	189.28	192.9	2.971	-2.387	-1.255	1.1291	1.3946
50	185.58	191.71	194.52	3.6276	184.39	190.33	193.69	3.5512	-2.0321	-1.3766	-0.8334	0.48753
55	188.18	192.59	199.91	4.3681	189.02	193.18	199.76	4.3932	-1.8125	0.59594	4.2332	2.2457
100	187.11	191.24	195.16	3.0167	184.88	188.34	193.09	3.4837	-8.0266	-2.9003	2.2995	3.929
105	184.81	192.02	196.26	4.5762	182.47	190.44	196.88	5.2772	-4.3509	-1.584	0.6274	2.1657

Device Test: 73.4 _EXT_CLOCK|Delay/SYNC_to_SW4/5/5/////1.8///@SYNC_SW_DELAY_VIN_5V





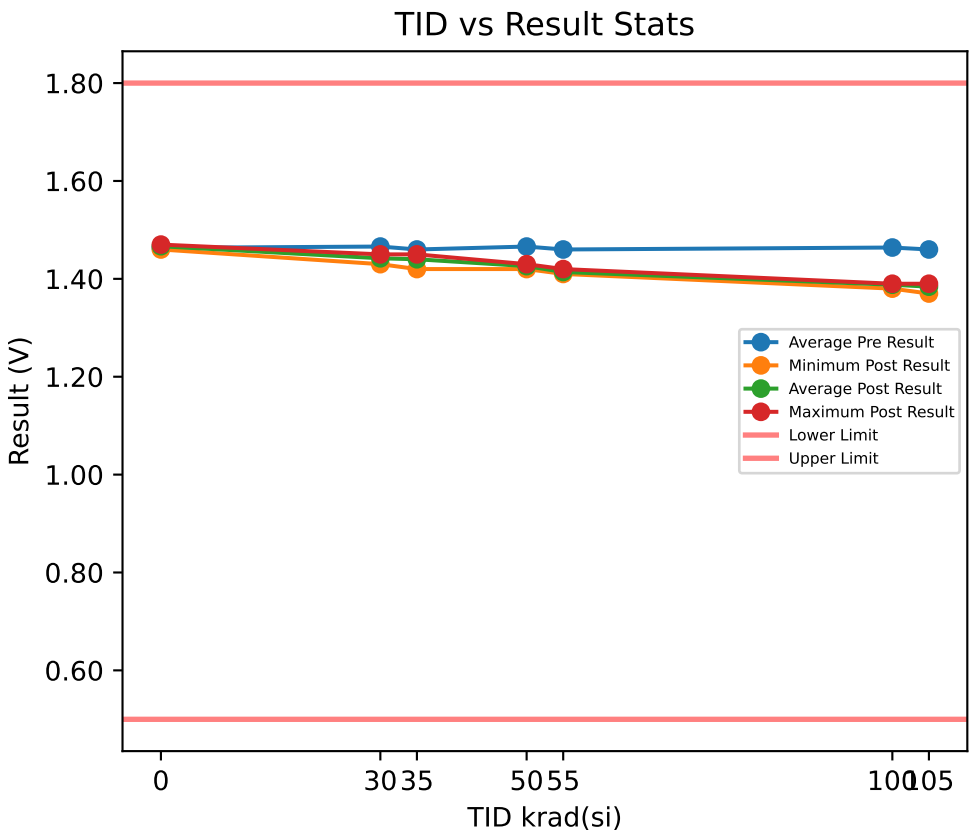
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

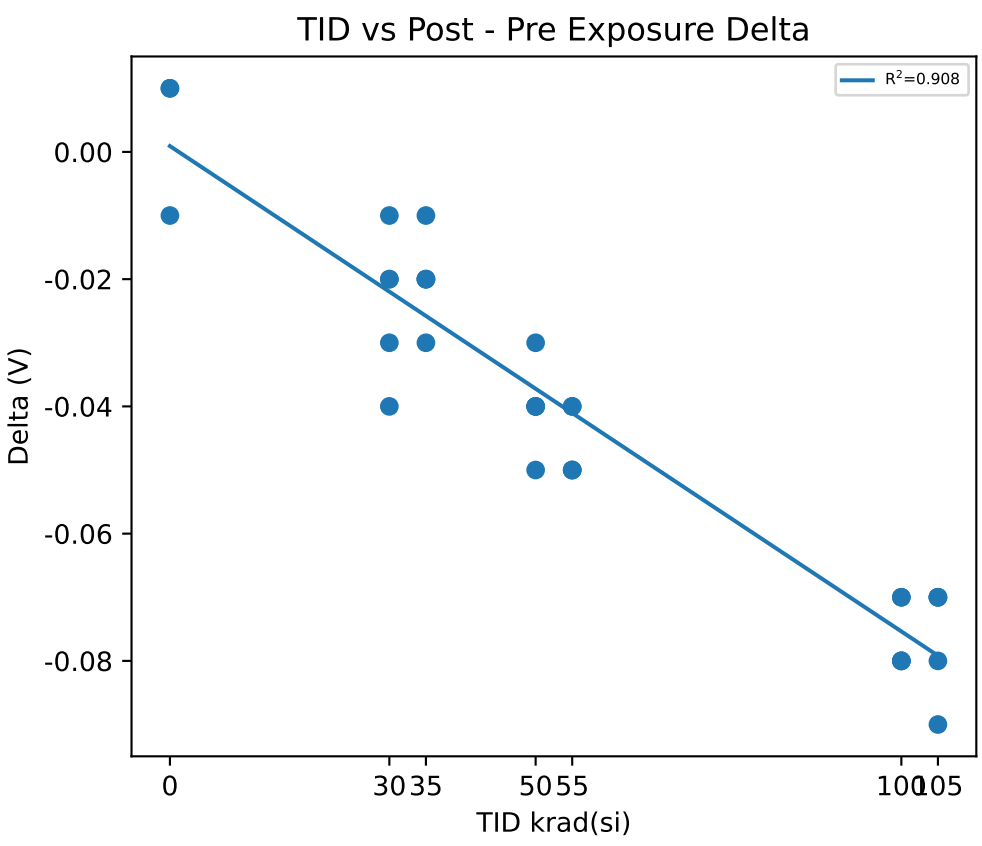
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	192.26	190.67	-1.59
2	0	CU2	191.92	189.04	-2.8758
3	0	CU3	199.12	198.36	-0.7592
11	30	Unbiased-30krad	192.57	192.95	0.3785
12	30	Unbiased-30krad	187.67	184.03	-3.637
13	30	Unbiased-30krad	186.04	185.28	-0.7596
14	30	Unbiased-30krad	193.14	190.99	-2.1431
15	30	Unbiased-30krad	194.14	192.75	-1.3988
16	35	Biased-30krad	193.36	194.24	0.8833
17	35	Biased-30krad	195.66	194.45	-1.2111
18	35	Biased-30krad	186.49	186	-0.4881
19	35	Biased-30krad	191.21	189.93	-1.2803
20	35	Biased-30krad	188.49	187.06	-1.4313
30	50	Unbiased-50krad	184.08	184.69	0.6159
31	50	Unbiased-50krad	186.59	185.17	-1.4195
32	50	Unbiased-50krad	201.75	198.93	-2.8205
33	50	Unbiased-50krad	194.74	191.65	-3.0871
34	50	Unbiased-50krad	195.91	194.29	-1.6196
40	55	Biased-50krad	196.78	195.59	-1.182
41	55	Biased-50krad	193.14	191.14	-2.0003
42	55	Biased-50krad	196.33	192.03	-4.3013
43	55	Biased-50krad	195.31	194.94	-0.3682
44	55	Biased-50krad	194.78	194.57	-0.2033
45	100	Unbiased-100krad	192.93	188.46	-4.4677
46	100	Unbiased-100krad	186.87	191.23	4.3634
47	100	Unbiased-100krad	193.28	192.45	-0.833
48	100	Unbiased-100krad	195.09	187.79	-7.3063
49	100	Unbiased-100krad	200.86	197.39	-3.467
50	105	Biased-100krad	194.63	194.23	-0.3981
51	105	Biased-100krad	190.44	193.52	3.0814
52	105	Biased-100krad	192.82	187.63	-5.1894
53	105	Biased-100krad	192.54	191.1	-1.443
54	105	Biased-100krad	190.64	197.71	7.0776

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	191.92	194.43	199.12	4.0598	189.04	192.69	198.36	4.9746	-2.8758	-1.7417	-0.7592	1.0664
30	186.04	190.71	194.14	3.6135	184.03	189.2	192.95	4.2409	-3.637	-1.512	0.3785	1.5056
35	186.49	191.04	195.66	3.6721	186	190.34	194.45	3.9322	-1.4313	-0.7055	0.8833	0.95973
50	184.08	192.61	201.75	7.2126	184.69	190.95	198.93	6.0815	-3.0871	-1.6662	0.6159	1.4682
55	193.14	195.27	196.78	1.4286	191.14	193.66	195.59	1.9505	-4.3013	-1.611	-0.2033	1.6658
100	186.87	193.81	200.86	5.0125	187.79	191.46	197.39	3.8297	-7.3063	-2.3421	4.3634	4.4065
105	190.44	192.21	194.63	1.7293	187.63	192.84	197.71	3.7508	-5.1894	0.6257	7.0776	4.6583

Device Test: 73.5 _EXT_CLOCK|VIH/SYNC/5/5/////1.8///@SYNC_SW_VIH_VIN_5V





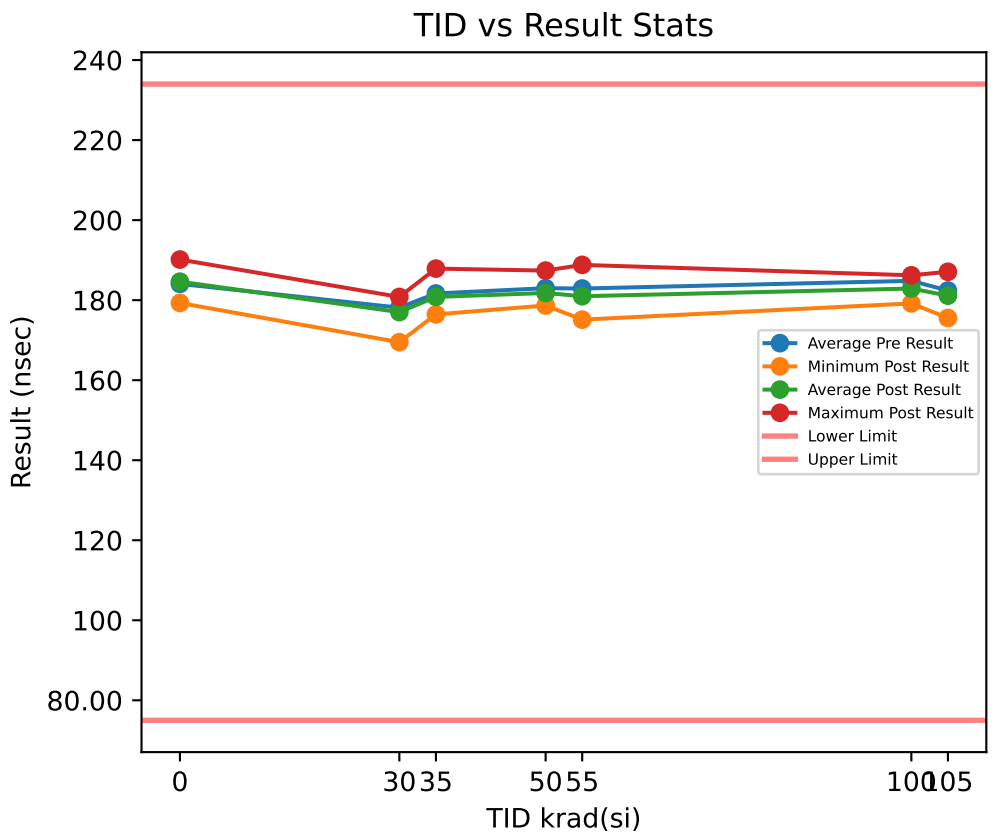
Test Results (Lower Limit = 0.5, Upper Limit = 1.8 (V))

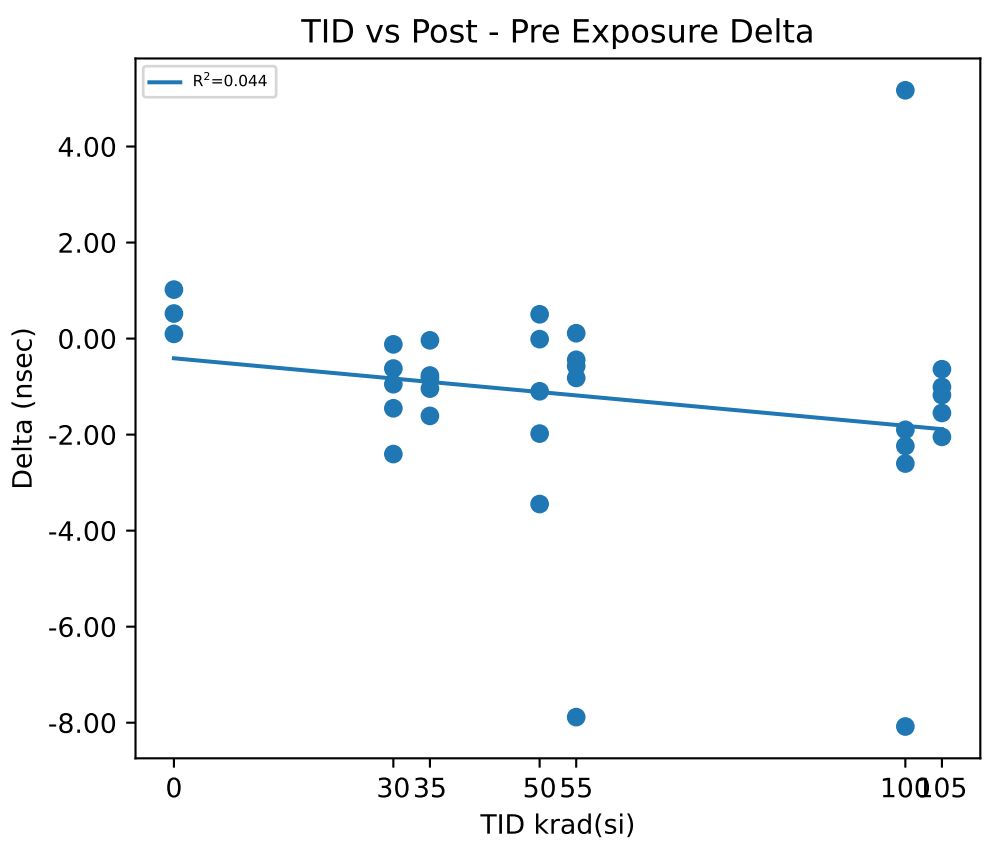
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.46	1.47	0.01
2	0	CU2	1.48	1.47	-0.01
3	0	CU3	1.45	1.46	0.01
11	30	Unbiased-30krad	1.47	1.44	-0.03
12	30	Unbiased-30krad	1.45	1.43	-0.02
13	30	Unbiased-30krad	1.48	1.44	-0.04
14	30	Unbiased-30krad	1.46	1.45	-0.01
15	30	Unbiased-30krad	1.47	1.45	-0.02
16	35	Biased-30krad	1.45	1.43	-0.02
17	35	Biased-30krad	1.46	1.45	-0.01
18	35	Biased-30krad	1.45	1.42	-0.03
19	35	Biased-30krad	1.47	1.45	-0.02
20	35	Biased-30krad	1.47	1.45	-0.02
30	50	Unbiased-50krad	1.46	1.42	-0.04
31	50	Unbiased-50krad	1.47	1.43	-0.04
32	50	Unbiased-50krad	1.46	1.42	-0.04
33	50	Unbiased-50krad	1.46	1.43	-0.03
34	50	Unbiased-50krad	1.48	1.43	-0.05
40	55	Biased-50krad	1.47	1.42	-0.05
41	55	Biased-50krad	1.46	1.41	-0.05
42	55	Biased-50krad	1.45	1.41	-0.04
43	55	Biased-50krad	1.46	1.41	-0.05
44	55	Biased-50krad	1.46	1.42	-0.04
45	100	Unbiased-100krad	1.46	1.39	-0.07
46	100	Unbiased-100krad	1.46	1.38	-0.08
47	100	Unbiased-100krad	1.47	1.39	-0.08
48	100	Unbiased-100krad	1.47	1.39	-0.08
49	100	Unbiased-100krad	1.46	1.39	-0.07
50	105	Biased-100krad	1.46	1.39	-0.07
51	105	Biased-100krad	1.46	1.38	-0.08
52	105	Biased-100krad	1.46	1.37	-0.09
53	105	Biased-100krad	1.46	1.39	-0.07
54	105	Biased-100krad	1.46	1.39	-0.07

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.45	1.4633	1.48	0.015275	1.46	1.4667	1.47	0.0057735	-0.01	0.0033333	0.01	0.011547
30	1.45	1.466	1.48	0.011402	1.43	1.442	1.45	0.0083666	-0.04	-0.024	-0.01	0.011402
35	1.45	1.46	1.47	0.01	1.42	1.44	1.45	0.014142	-0.03	-0.02	-0.01	0.0070711
50	1.46	1.466	1.48	0.0089443	1.42	1.426	1.43	0.0054772	-0.05	-0.04	-0.03	0.0070711
55	1.45	1.46	1.47	0.0070711	1.41	1.414	1.42	0.0054772	-0.05	-0.046	-0.04	0.0054772
100	1.46	1.464	1.47	0.0054772	1.38	1.388	1.39	0.0044721	-0.08	-0.076	-0.07	0.0054772
105	1.46	1.46	1.46	0	1.37	1.384	1.39	0.0089443	-0.09	-0.076	-0.07	0.0089443

Device Test: 74.13 _EXT_CLOCK|Delay/SYNC_to_SW1/7/7/////1.8///@SYNC_SW_DELAY_VIN_7V





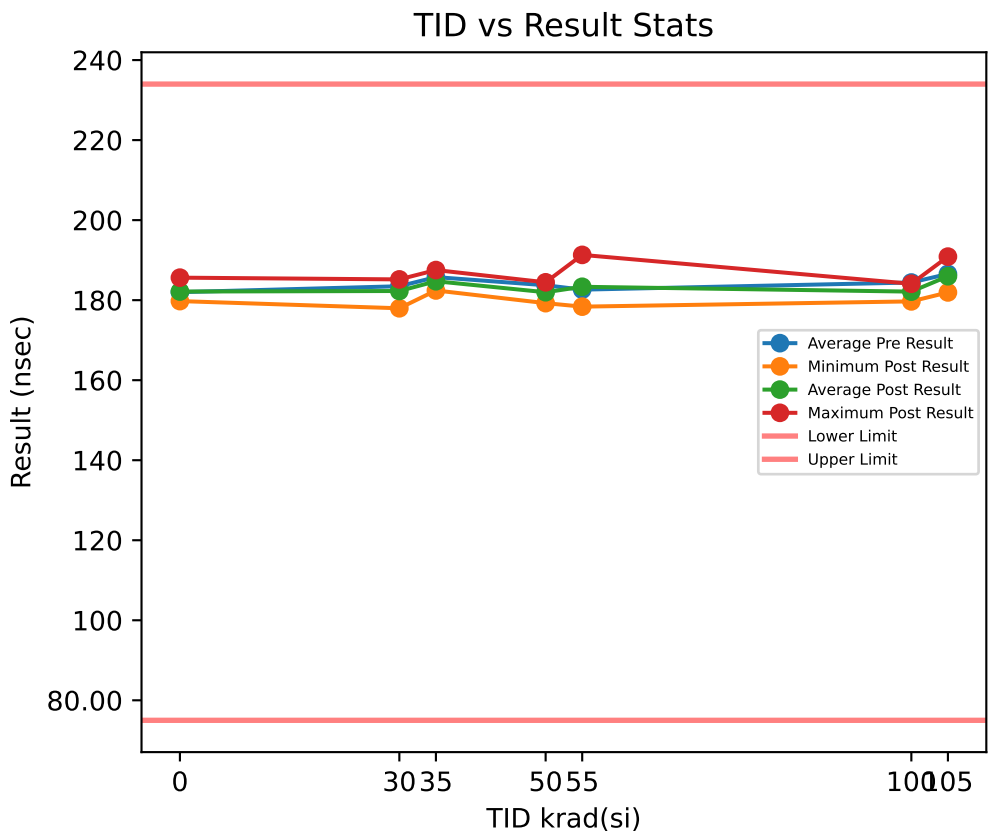
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

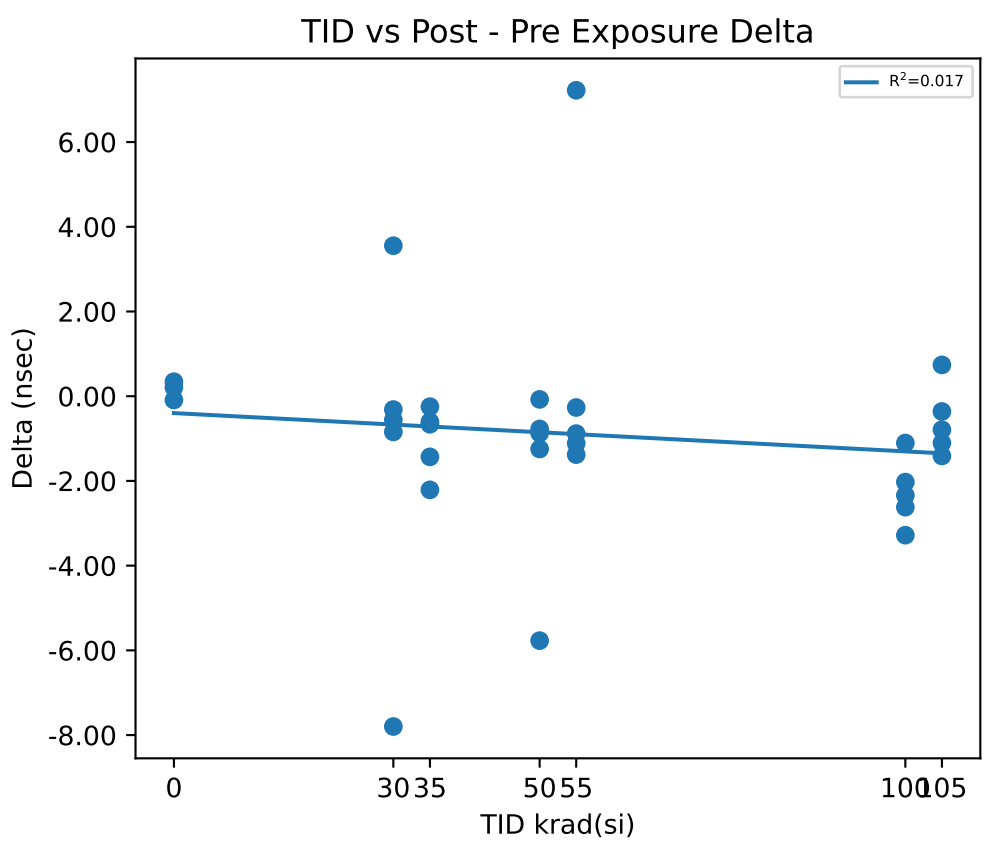
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	178.77	179.3	0.5219
2	0	CU2	189.13	190.15	1.0204
3	0	CU3	184.31	184.41	0.098
11	30	Unbiased-30krad	179.32	177.87	-1.4518
12	30	Unbiased-30krad	180.85	178.44	-2.4052
13	30	Unbiased-30krad	180.92	180.8	-0.1202
14	30	Unbiased-30krad	179.1	178.47	-0.624
15	30	Unbiased-30krad	170.45	169.5	-0.95
16	35	Biased-30krad	177.27	176.44	-0.8301
17	35	Biased-30krad	179.36	178.31	-1.0421
18	35	Biased-30krad	189.5	187.89	-1.6102
19	35	Biased-30krad	179.82	179.79	-0.0363
20	35	Biased-30krad	182.39	181.63	-0.769
30	50	Unbiased-50krad	178.56	179.07	0.5059
31	50	Unbiased-50krad	183.44	181.46	-1.9786
32	50	Unbiased-50krad	187.41	187.39	-0.0115
33	50	Unbiased-50krad	185.82	182.37	-3.446
34	50	Unbiased-50krad	179.77	178.67	-1.0976
40	55	Biased-50krad	176.3	176.41	0.1116
41	55	Biased-50krad	175.57	175.13	-0.442
42	55	Biased-50krad	185.86	177.98	-7.8835
43	55	Biased-50krad	187.41	186.59	-0.8202
44	55	Biased-50krad	189.39	188.82	-0.5743
45	100	Unbiased-100krad	187.56	185.33	-2.2368
46	100	Unbiased-100krad	188.12	186.22	-1.9001
47	100	Unbiased-100krad	178.5	183.67	5.1711
48	100	Unbiased-100krad	182.72	180.12	-2.6026
49	100	Unbiased-100krad	187.27	179.19	-8.0792
50	105	Biased-100krad	176.8	175.62	-1.1772
51	105	Biased-100krad	187.73	187.09	-0.6377
52	105	Biased-100krad	177.59	175.55	-2.047
53	105	Biased-100krad	182.94	181.93	-1.0071
54	105	Biased-100krad	186.99	185.44	-1.5493

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	178.77	184.07	189.13	5.1828	179.3	184.62	190.15	5.4308	0.098	0.54677	1.0204	0.4617
30	170.45	178.13	180.92	4.3743	169.5	177.02	180.8	4.3514	-2.4052	-1.1102	-0.1202	0.87119
35	177.27	181.67	189.5	4.7401	176.44	180.81	187.89	4.3899	-1.6102	-0.85754	-0.0363	0.56648
50	178.56	183	187.41	3.7975	178.67	181.79	187.39	3.4998	-3.446	-1.2056	0.5059	1.5798
55	175.57	182.91	189.39	6.4921	175.13	180.99	188.82	6.2662	-7.8835	-1.9217	0.1116	3.3502
100	178.5	184.83	188.12	4.1474	179.19	182.9	186.22	3.1223	-8.0792	-1.9295	5.1711	4.7113
105	176.8	182.41	187.73	5.1059	175.55	181.13	187.09	5.3928	-2.047	-1.2837	-0.6377	0.53813

Device Test: 74.14 _EXT_CLOCK|Delay/SYNC_to_SW2/7/7/////1.8///@SYNC_SW_DELAY_VIN_7V





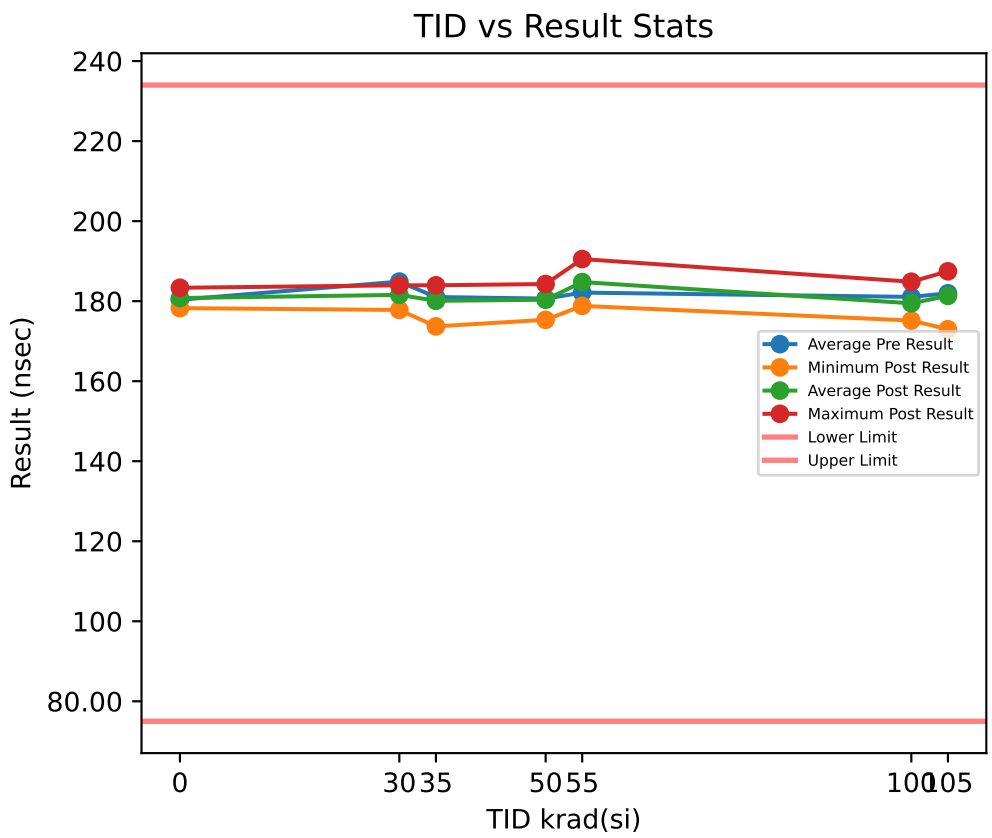
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

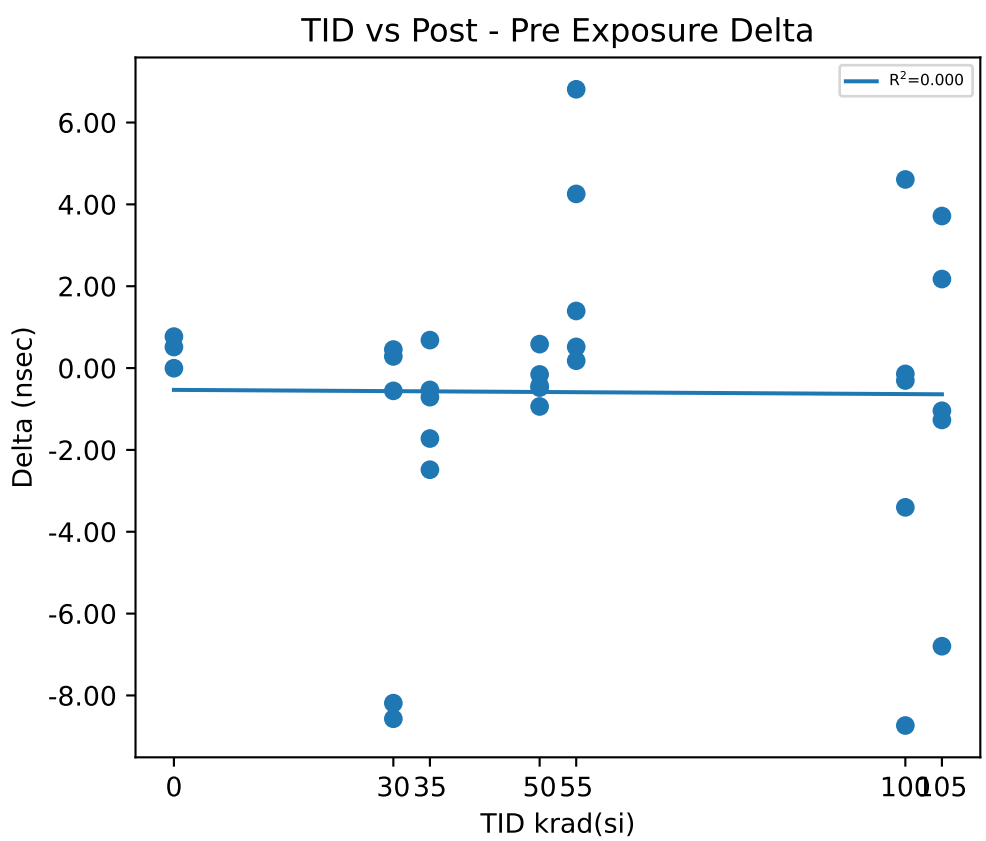
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	185.28	185.62	0.3425
2	0	CU2	179.86	179.77	-0.0889
3	0	CU3	180.86	181.07	0.2089
11	30	Unbiased-30krad	178.29	177.97	-0.315
12	30	Unbiased-30krad	185.75	185.19	-0.5582
13	30	Unbiased-30krad	188.51	180.71	-7.7978
14	30	Unbiased-30krad	183.39	182.54	-0.8433
15	30	Unbiased-30krad	181.47	185.02	3.5535
16	35	Biased-30krad	183.09	182.43	-0.6618
17	35	Biased-30krad	186.15	183.94	-2.2108
18	35	Biased-30krad	188.96	187.52	-1.4318
19	35	Biased-30krad	185.59	185.35	-0.2469
20	35	Biased-30krad	185.01	184.4	-0.6024
30	50	Unbiased-50krad	179.33	179.25	-0.075
31	50	Unbiased-50krad	183.54	182.77	-0.7735
32	50	Unbiased-50krad	186.4	180.63	-5.7704
33	50	Unbiased-50krad	185.71	184.46	-1.2462
34	50	Unbiased-50krad	183.66	182.79	-0.8687
40	55	Biased-50krad	184.09	191.31	7.2224
41	55	Biased-50krad	179.76	178.38	-1.3786
42	55	Biased-50krad	182.68	181.8	-0.8832
43	55	Biased-50krad	183.94	182.83	-1.1145
44	55	Biased-50krad	182.67	182.4	-0.2667
45	100	Unbiased-100krad	180.8	179.69	-1.1044
46	100	Unbiased-100krad	184.39	181.11	-3.2812
47	100	Unbiased-100krad	186.44	184.1	-2.3404
48	100	Unbiased-100krad	184.39	182.37	-2.0278
49	100	Unbiased-100krad	186.03	183.41	-2.6196
50	105	Biased-100krad	182.91	183.65	0.7387
51	105	Biased-100krad	183.35	181.93	-1.4105
52	105	Biased-100krad	188.71	187.61	-1.104
53	105	Biased-100krad	191.24	190.88	-0.3603
54	105	Biased-100krad	186.61	185.82	-0.7907

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	179.86	182	185.28	2.8862	179.77	182.15	185.62	3.075	-0.0889	0.15417	0.3425	0.22085
30	178.29	183.48	188.51	3.9189	177.97	182.29	185.19	3.045	-7.7978	-1.1922	3.5535	4.1064
35	183.09	185.76	188.96	2.1271	182.43	184.73	187.52	1.8862	-2.2108	-1.0307	-0.2469	0.78857
50	179.33	183.73	186.4	2.7598	179.25	181.98	184.46	2.0437	-5.7704	-1.7468	-0.075	2.2887
55	179.76	182.63	184.09	1.7397	178.38	183.35	191.31	4.7882	-1.3786	0.71588	7.2224	3.6604
100	180.8	184.41	186.44	2.223	179.69	182.14	184.1	1.7696	-3.2812	-2.2747	-1.1044	0.80107
105	182.91	186.56	191.24	3.5431	181.93	185.98	190.88	3.4821	-1.4105	-0.58536	0.7387	0.83603

Device Test: 74.15 _EXT_CLOCK|Delay/SYNC_to_SW3/7/7/////1.8///@SYNC_SW_DELAY_VIN_7V





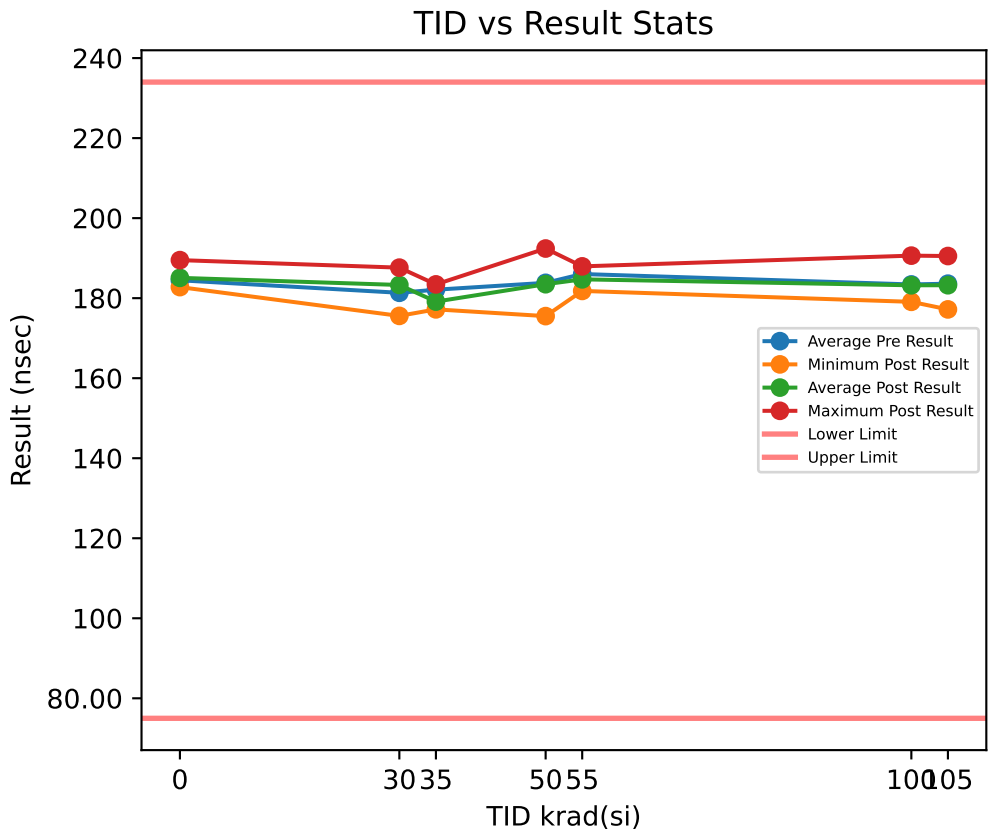
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

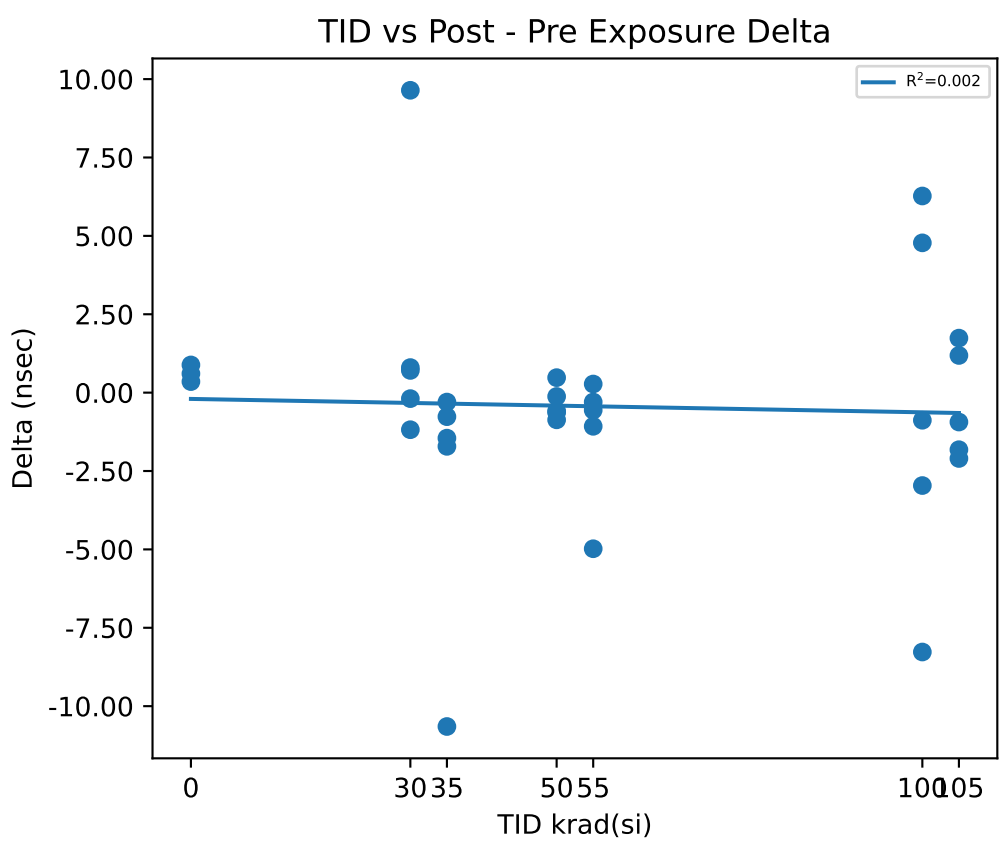
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	180.23	180.74	0.5142
2	0	CU2	182.58	183.35	0.7688
3	0	CU3	178.26	178.26	-0.0035
11	30	Unbiased-30krad	181.07	181.52	0.4529
12	30	Unbiased-30krad	183.22	183.5	0.2846
13	30	Unbiased-30krad	186.37	177.8	-8.5698
14	30	Unbiased-30krad	189.26	181.07	-8.188
15	30	Unbiased-30krad	184.52	183.96	-0.5568
16	35	Biased-30krad	184.5	183.79	-0.7111
17	35	Biased-30krad	185.69	183.96	-1.722
18	35	Biased-30krad	178.69	179.37	0.6831
19	35	Biased-30krad	180.14	179.6	-0.5343
20	35	Biased-30krad	176.18	173.7	-2.4843
30	50	Unbiased-50krad	174.75	175.34	0.5854
31	50	Unbiased-50krad	181.64	181.16	-0.4769
32	50	Unbiased-50krad	182.57	181.63	-0.9385
33	50	Unbiased-50krad	179.79	179.36	-0.4308
34	50	Unbiased-50krad	184.44	184.28	-0.1555
40	55	Biased-50krad	179.98	186.8	6.8123
41	55	Biased-50krad	180.46	184.72	4.2553
42	55	Biased-50krad	182.48	183	0.5172
43	55	Biased-50krad	177.42	178.82	1.3949
44	55	Biased-50krad	190.34	190.52	0.1794
45	100	Unbiased-100krad	183.47	180.06	-3.4035
46	100	Unbiased-100krad	183.9	175.16	-8.7346
47	100	Unbiased-100krad	180.25	184.86	4.6089
48	100	Unbiased-100krad	175.92	175.61	-0.3044
49	100	Unbiased-100krad	181.8	181.66	-0.1426
50	105	Biased-100krad	185.44	178.64	-6.7972
51	105	Biased-100krad	178.35	182.07	3.7152
52	105	Biased-100krad	174.02	172.98	-1.0436
53	105	Biased-100krad	185.29	187.47	2.1753
54	105	Biased-100krad	186.7	185.43	-1.2679

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	178.26	180.36	182.58	2.1636	178.26	180.78	183.35	2.5471	-0.0035	0.4265	0.7688	0.39355
30	181.07	184.89	189.26	3.1165	177.8	181.57	183.96	2.4438	-8.5698	-3.3154	0.4529	4.6401
35	176.18	181.04	185.69	3.9833	173.7	180.09	183.96	4.1914	-2.4843	-0.95372	0.6831	1.209
50	174.75	180.64	184.44	3.6936	175.34	180.35	184.28	3.313	-0.9385	-0.28326	0.5854	0.56114
55	177.42	182.14	190.34	4.9283	178.82	184.77	190.52	4.3525	0.1794	2.6318	6.8123	2.8341
100	175.92	181.07	183.9	3.2211	175.16	179.47	184.86	4.1102	-8.7346	-1.5952	4.6089	4.9119
105	174.02	181.96	186.7	5.5155	172.98	181.32	187.47	5.7446	-6.7972	-0.64364	3.7152	4.0423

Device Test: 74.16 _EXT_CLOCK|Delay/SYNC_to_SW4/7/7/////1.8///@SYNC_SW_DELAY_VIN_7V





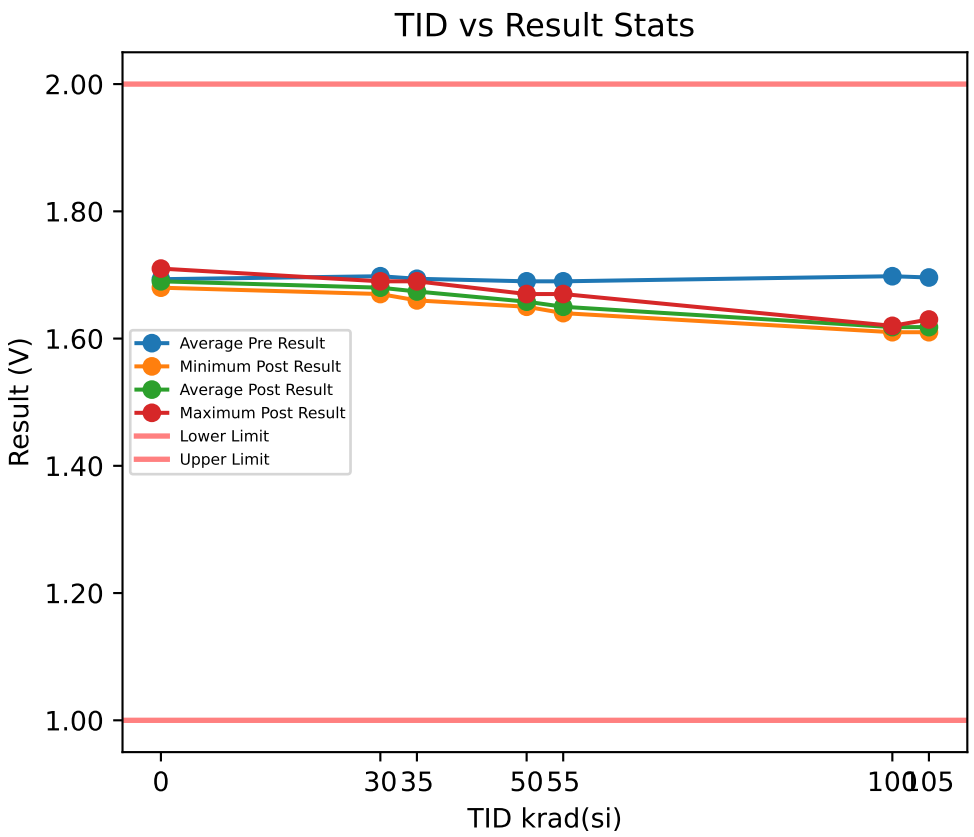
Test Results (Lower Limit = 75.0, Upper Limit = 234.0 (nsec))

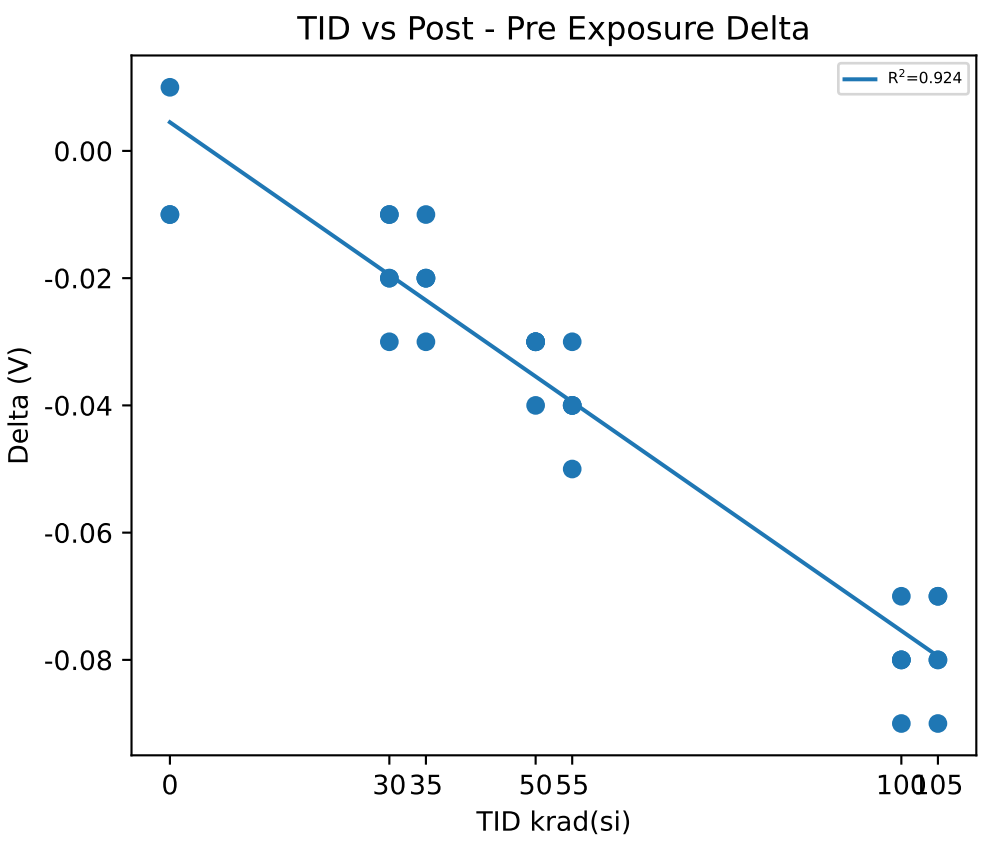
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	182.16	182.76	0.6053
2	0	CU2	182.08	182.96	0.8834
3	0	CU3	189.16	189.51	0.352
11	30	Unbiased-30krad	183.82	184.62	0.7995
12	30	Unbiased-30krad	176.75	175.57	-1.1825
13	30	Unbiased-30krad	176.38	186.02	9.6435
14	30	Unbiased-30krad	182.84	182.65	-0.1908
15	30	Unbiased-30krad	186.92	187.63	0.7085
16	35	Biased-30krad	185.16	183.44	-1.7133
17	35	Biased-30krad	188.97	178.32	-10.649
18	35	Biased-30krad	179.06	178.29	-0.7667
19	35	Biased-30krad	178.74	178.44	-0.3007
20	35	Biased-30krad	178.65	177.2	-1.451
30	50	Unbiased-50krad	176.96	177.44	0.4782
31	50	Unbiased-50krad	175.64	175.51	-0.1227
32	50	Unbiased-50krad	193.27	192.4	-0.8673
33	50	Unbiased-50krad	185.24	184.66	-0.5842
34	50	Unbiased-50krad	188.04	187.41	-0.6354
40	55	Biased-50krad	188.79	183.81	-4.9792
41	55	Biased-50krad	182.37	181.81	-0.5596
42	55	Biased-50krad	183.38	182.3	-1.0743
43	55	Biased-50krad	188.24	187.95	-0.2987
44	55	Biased-50krad	187.37	187.65	0.2747
45	100	Unbiased-100krad	182.24	179.28	-2.9631
46	100	Unbiased-100krad	178.63	183.4	4.7774
47	100	Unbiased-100krad	184.56	183.68	-0.8809
48	100	Unbiased-100krad	187.36	179.08	-8.2729
49	100	Unbiased-100krad	184.36	190.63	6.2722
50	105	Biased-100krad	188.54	186.44	-2.0997
51	105	Biased-100krad	179.04	178.1	-0.9378
52	105	Biased-100krad	175.45	177.19	1.7387
53	105	Biased-100krad	185.72	183.9	-1.8202
54	105	Biased-100krad	189.34	190.53	1.1859

Test Statistics (nsec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	182.08	184.47	189.16	4.062	182.76	185.08	189.51	3.8366	0.352	0.61357	0.8834	0.2658
30	176.38	181.34	186.92	4.6151	175.57	183.3	187.63	4.693	-1.1825	1.9556	9.6435	4.3718
35	178.65	182.12	188.97	4.7157	177.2	179.14	183.44	2.4567	-10.649	-2.9761	-0.3007	4.3253
50	175.64	183.83	193.27	7.4703	175.51	183.48	192.4	7.0075	-0.8673	-0.34628	0.4782	0.53418
55	182.37	186.03	188.79	2.9489	181.81	184.7	187.95	2.9209	-4.9792	-1.3274	0.2747	2.0985
100	178.63	183.43	187.36	3.2421	179.08	183.22	190.63	4.6838	-8.2729	-0.21346	6.2722	5.9147
105	175.45	183.62	189.34	6.1047	177.19	183.23	190.53	5.6307	-2.0997	-0.38662	1.7387	1.7524

Device Test: 74.17 _EXT_CLOCK|VIH/SYNC/7/7/////1.8///@SYNC_SW_VIH_VIN_7V





Test Results (Lower Limit = 1.0, Upper Limit = 2.0 (V))

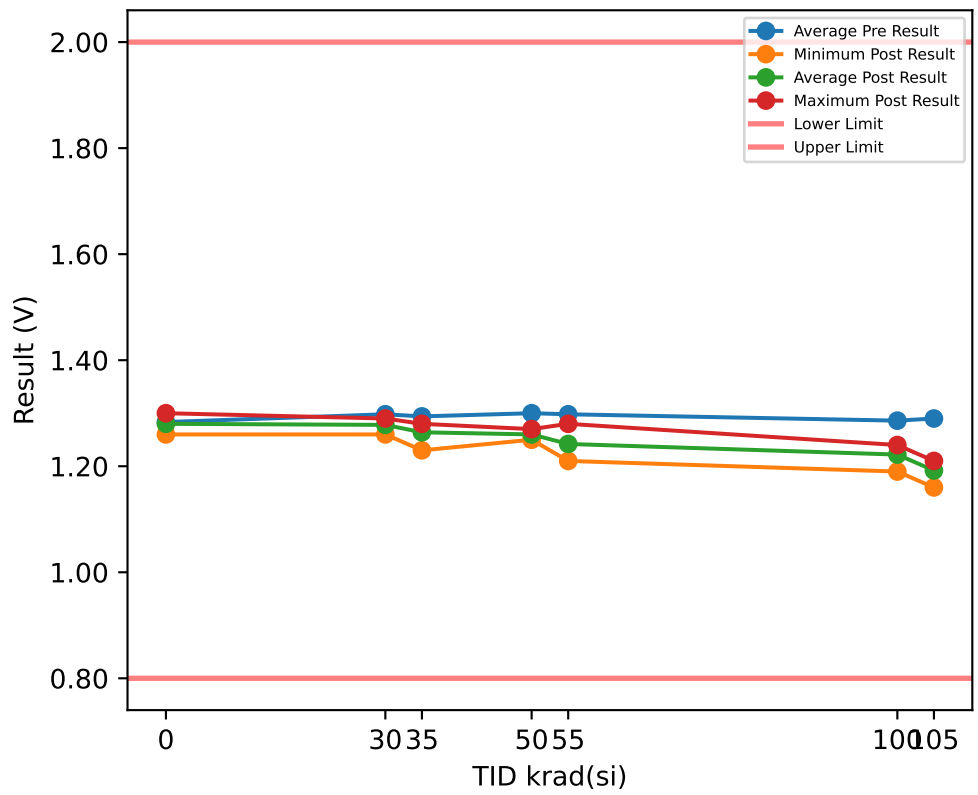
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.69	1.68	-0.01
2	0	CU2	1.7	1.71	0.01
3	0	CU3	1.69	1.68	-0.01
11	30	Unbiased-30krad	1.7	1.68	-0.02
12	30	Unbiased-30krad	1.68	1.67	-0.01
13	30	Unbiased-30krad	1.7	1.68	-0.02
14	30	Unbiased-30krad	1.71	1.68	-0.03
15	30	Unbiased-30krad	1.7	1.69	-0.01
16	35	Biased-30krad	1.69	1.66	-0.03
17	35	Biased-30krad	1.69	1.68	-0.01
18	35	Biased-30krad	1.68	1.66	-0.02
19	35	Biased-30krad	1.7	1.68	-0.02
20	35	Biased-30krad	1.71	1.69	-0.02
30	50	Unbiased-50krad	1.68	1.65	-0.03
31	50	Unbiased-50krad	1.7	1.67	-0.03
32	50	Unbiased-50krad	1.69	1.65	-0.04
33	50	Unbiased-50krad	1.69	1.66	-0.03
34	50	Unbiased-50krad	1.69	1.66	-0.03
40	55	Biased-50krad	1.7	1.67	-0.03
41	55	Biased-50krad	1.69	1.64	-0.05
42	55	Biased-50krad	1.68	1.64	-0.04
43	55	Biased-50krad	1.69	1.65	-0.04
44	55	Biased-50krad	1.69	1.65	-0.04
45	100	Unbiased-100krad	1.7	1.62	-0.08
46	100	Unbiased-100krad	1.69	1.61	-0.08
47	100	Unbiased-100krad	1.71	1.62	-0.09
48	100	Unbiased-100krad	1.7	1.62	-0.08
49	100	Unbiased-100krad	1.69	1.62	-0.07
50	105	Biased-100krad	1.7	1.63	-0.07
51	105	Biased-100krad	1.7	1.61	-0.09
52	105	Biased-100krad	1.69	1.61	-0.08
53	105	Biased-100krad	1.7	1.62	-0.08
54	105	Biased-100krad	1.69	1.62	-0.07

Test Statistics (V)

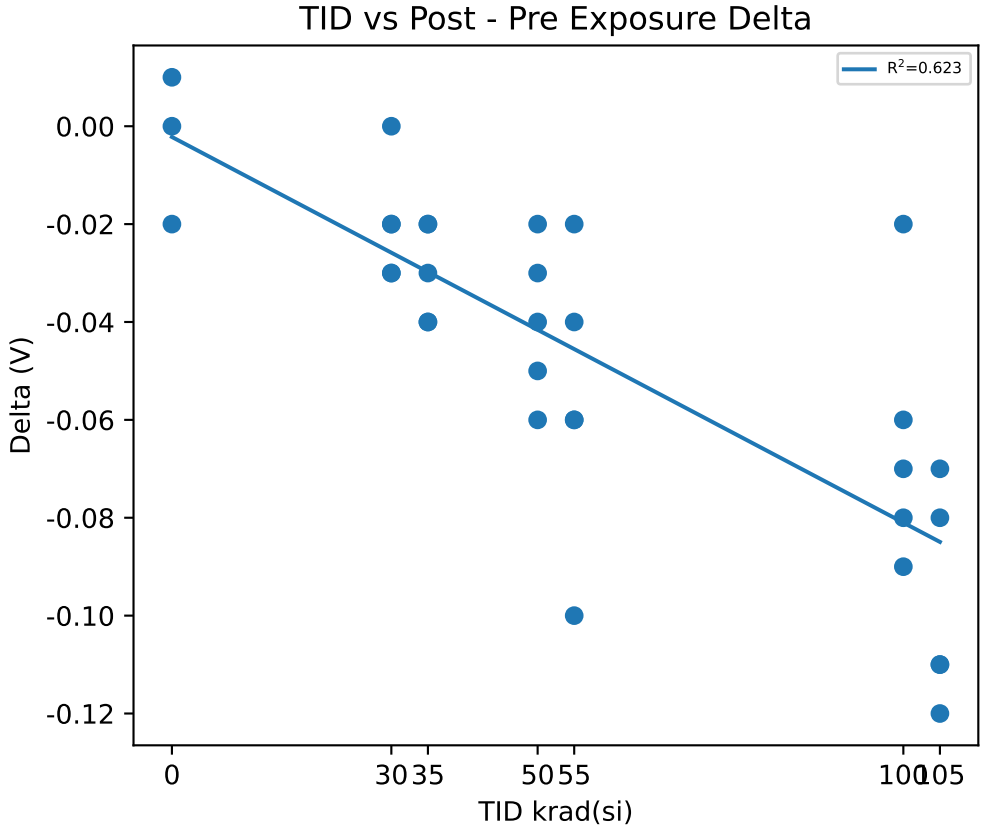
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.69	1.6933	1.7	0.0057735	1.68	1.69	1.71	0.017321	-0.01	-0.0033333	0.01	0.011547
30	1.68	1.698	1.71	0.010954	1.67	1.68	1.69	0.0070711	-0.03	-0.018	-0.01	0.0083666
35	1.68	1.694	1.71	0.011402	1.66	1.674	1.69	0.013416	-0.03	-0.02	-0.01	0.0070711
50	1.68	1.69	1.7	0.0070711	1.65	1.658	1.67	0.0083666	-0.04	-0.032	-0.03	0.0044721
55	1.68	1.69	1.7	0.0070711	1.64	1.65	1.67	0.012247	-0.05	-0.04	-0.03	0.0070711
100	1.69	1.698	1.71	0.0083666	1.61	1.618	1.62	0.0044721	-0.09	-0.08	-0.07	0.0070711
105	1.69	1.696	1.7	0.0054772	1.61	1.618	1.63	0.0083666	-0.09	-0.078	-0.07	0.0083666

Device Test: 74.18 _EXT_CLOCK|VIL/SYNC/7/7/////1.8///@SYNC_VIL

TID vs Result Stats



TID vs Post - Pre Exposure Delta



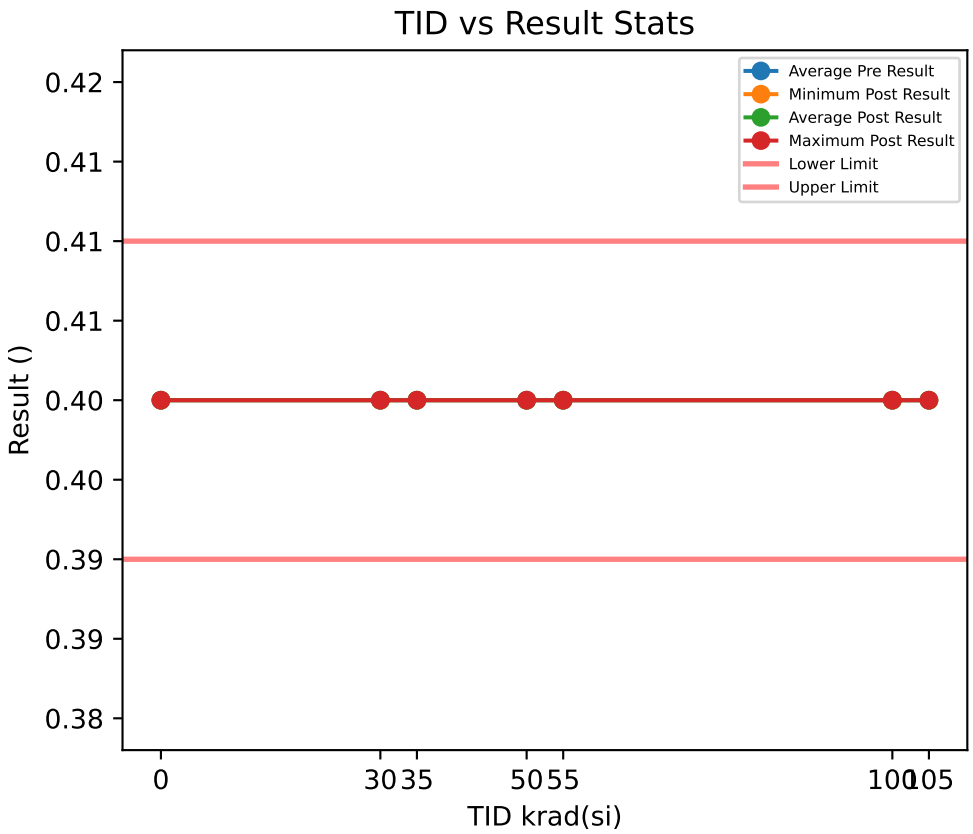
Test Results (Lower Limit = 0.8, Upper Limit = 2.0 (V))

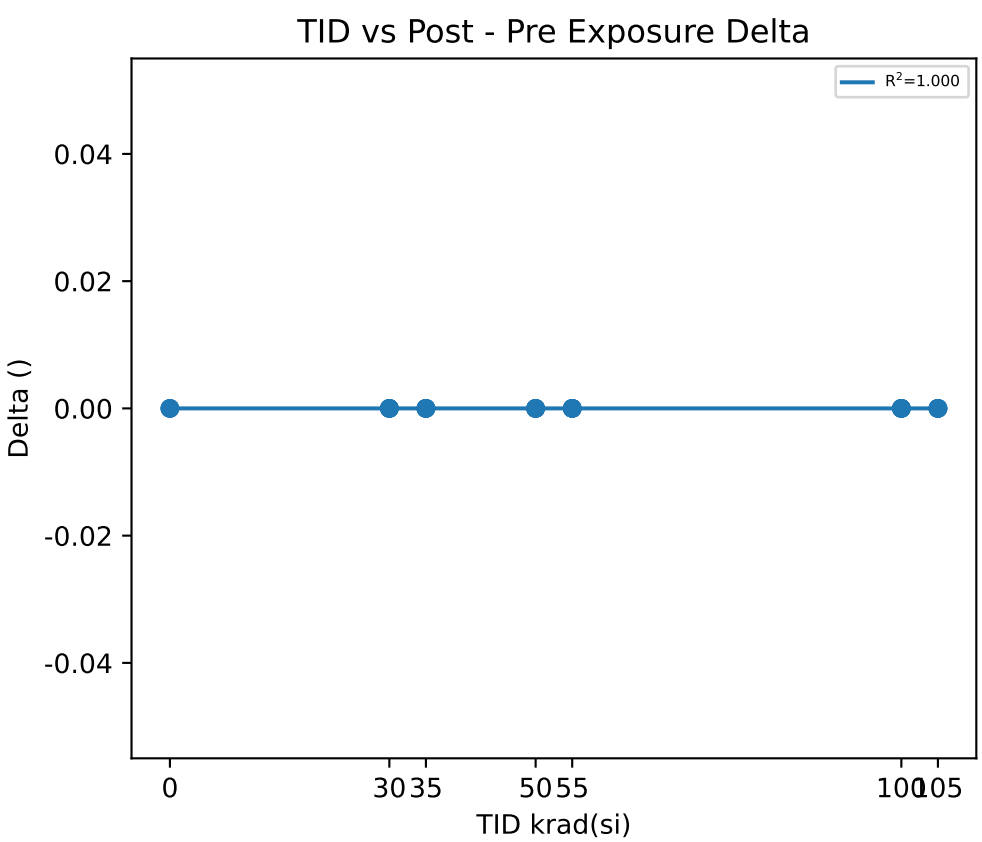
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.29	1.3	0.01
2	0	CU2	1.3	1.28	-0.02
3	0	CU3	1.26	1.26	0
11	30	Unbiased-30krad	1.29	1.26	-0.03
12	30	Unbiased-30krad	1.31	1.28	-0.03
13	30	Unbiased-30krad	1.29	1.29	0
14	30	Unbiased-30krad	1.29	1.27	-0.02
15	30	Unbiased-30krad	1.31	1.29	-0.02
16	35	Biased-30krad	1.3	1.28	-0.02
17	35	Biased-30krad	1.31	1.27	-0.04
18	35	Biased-30krad	1.25	1.23	-0.02
19	35	Biased-30krad	1.31	1.27	-0.04
20	35	Biased-30krad	1.3	1.27	-0.03
30	50	Unbiased-50krad	1.29	1.27	-0.02
31	50	Unbiased-50krad	1.3	1.26	-0.04
32	50	Unbiased-50krad	1.3	1.25	-0.05
33	50	Unbiased-50krad	1.3	1.27	-0.03
34	50	Unbiased-50krad	1.31	1.25	-0.06
40	55	Biased-50krad	1.3	1.28	-0.02
41	55	Biased-50krad	1.31	1.21	-0.1
42	55	Biased-50krad	1.3	1.24	-0.06
43	55	Biased-50krad	1.3	1.24	-0.06
44	55	Biased-50krad	1.28	1.24	-0.04
45	100	Unbiased-100krad	1.28	1.22	-0.06
46	100	Unbiased-100krad	1.32	1.24	-0.08
47	100	Unbiased-100krad	1.32	1.23	-0.09
48	100	Unbiased-100krad	1.26	1.19	-0.07
49	100	Unbiased-100krad	1.25	1.23	-0.02
50	105	Biased-100krad	1.28	1.21	-0.07
51	105	Biased-100krad	1.31	1.2	-0.11
52	105	Biased-100krad	1.24	1.16	-0.08
53	105	Biased-100krad	1.31	1.19	-0.12
54	105	Biased-100krad	1.31	1.2	-0.11

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.26	1.2833	1.3	0.020817	1.26	1.28	1.3	0.02	-0.02	-0.0033333	0.01	0.015275
30	1.29	1.298	1.31	0.010954	1.26	1.278	1.29	0.013038	-0.03	-0.02	0	0.012247
35	1.25	1.294	1.31	0.0251	1.23	1.264	1.28	0.019494	-0.04	-0.03	-0.02	0.01
50	1.29	1.3	1.31	0.0070711	1.25	1.26	1.27	0.01	-0.06	-0.04	-0.02	0.015811
55	1.28	1.298	1.31	0.010954	1.21	1.242	1.28	0.0249	-0.1	-0.056	-0.02	0.029665
100	1.25	1.286	1.32	0.032863	1.19	1.222	1.24	0.019235	-0.09	-0.064	-0.02	0.027019
105	1.24	1.29	1.31	0.030822	1.16	1.192	1.21	0.019235	-0.12	-0.098	-0.07	0.021679

Device Test: 74.19 _EXT_CLOCK|GNG_DutyCyc40Pct/SYNC/7/7/////1.8///@SYNC_IN_DUTY_CYCLE_LOW





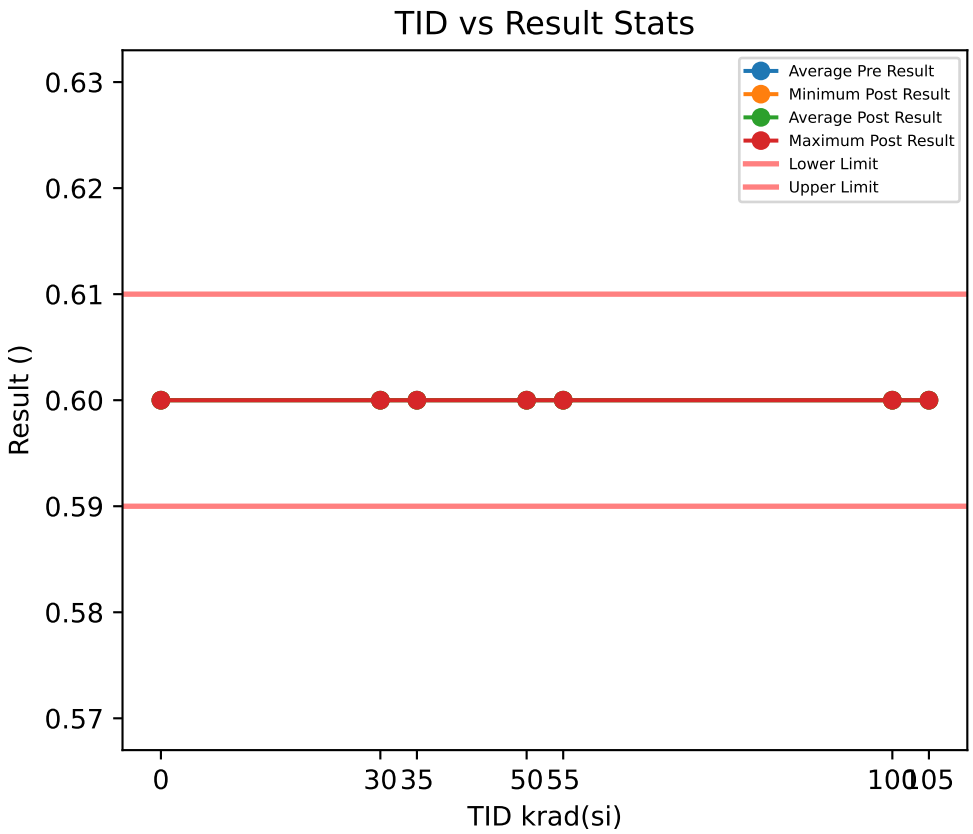
Test Results (Lower Limit = 0.39, Upper Limit = 0.41 ())

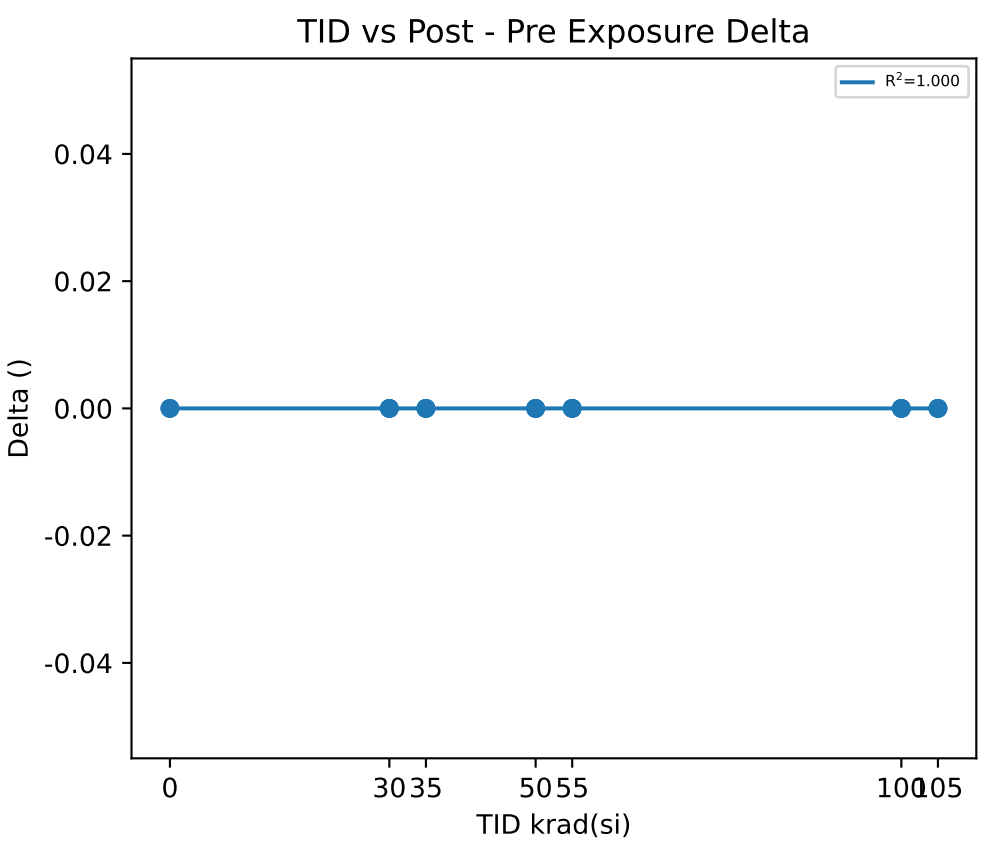
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.4	0.4	0
2	0	CU2	0.4	0.4	0
3	0	CU3	0.4	0.4	0
11	30	Unbiased-30krad	0.4	0.4	0
12	30	Unbiased-30krad	0.4	0.4	0
13	30	Unbiased-30krad	0.4	0.4	0
14	30	Unbiased-30krad	0.4	0.4	0
15	30	Unbiased-30krad	0.4	0.4	0
16	35	Biased-30krad	0.4	0.4	0
17	35	Biased-30krad	0.4	0.4	0
18	35	Biased-30krad	0.4	0.4	0
19	35	Biased-30krad	0.4	0.4	0
20	35	Biased-30krad	0.4	0.4	0
30	50	Unbiased-50krad	0.4	0.4	0
31	50	Unbiased-50krad	0.4	0.4	0
32	50	Unbiased-50krad	0.4	0.4	0
33	50	Unbiased-50krad	0.4	0.4	0
34	50	Unbiased-50krad	0.4	0.4	0
40	55	Biased-50krad	0.4	0.4	0
41	55	Biased-50krad	0.4	0.4	0
42	55	Biased-50krad	0.4	0.4	0
43	55	Biased-50krad	0.4	0.4	0
44	55	Biased-50krad	0.4	0.4	0
45	100	Unbiased-100krad	0.4	0.4	0
46	100	Unbiased-100krad	0.4	0.4	0
47	100	Unbiased-100krad	0.4	0.4	0
48	100	Unbiased-100krad	0.4	0.4	0
49	100	Unbiased-100krad	0.4	0.4	0
50	105	Biased-100krad	0.4	0.4	0
51	105	Biased-100krad	0.4	0.4	0
52	105	Biased-100krad	0.4	0.4	0
53	105	Biased-100krad	0.4	0.4	0
54	105	Biased-100krad	0.4	0.4	0

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4	0.4	0.4	0	0.4	0.4	0.4	0	0	0	0	0
30	0.4	0.4	0.4	0	0.4	0.4	0.4	0	0	0	0	0
35	0.4	0.4	0.4	0	0.4	0.4	0.4	0	0	0	0	0
50	0.4	0.4	0.4	0	0.4	0.4	0.4	0	0	0	0	0
55	0.4	0.4	0.4	0	0.4	0.4	0.4	0	0	0	0	0
100	0.4	0.4	0.4	0	0.4	0.4	0.4	0	0	0	0	0
105	0.4	0.4	0.4	0	0.4	0.4	0.4	0	0	0	0	0

Device Test: 74.20 _EXT_CLOCK|GNG_DutyCyc60Pct/SYNC/7/7//////1.8///@SYNC_IN_DUTY_CYCLE_HIGH





Test Results (Lower Limit = 0.59, Upper Limit = 0.61 ())

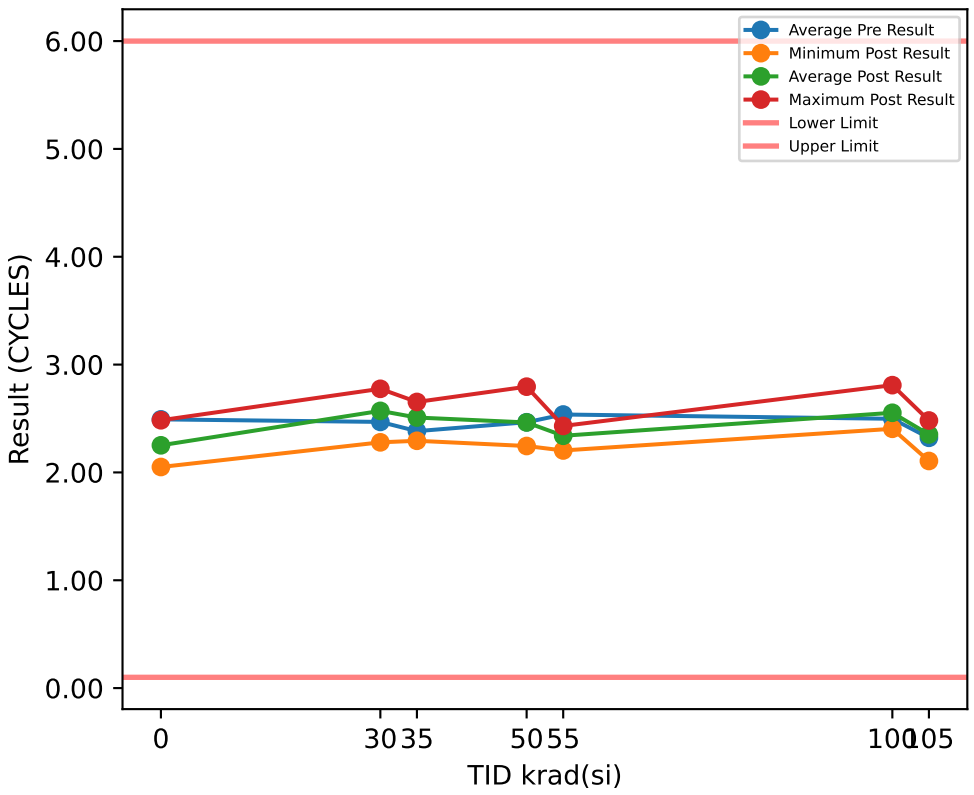
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.6	0.6	0
2	0	CU2	0.6	0.6	0
3	0	CU3	0.6	0.6	0
11	30	Unbiased-30krad	0.6	0.6	0
12	30	Unbiased-30krad	0.6	0.6	0
13	30	Unbiased-30krad	0.6	0.6	0
14	30	Unbiased-30krad	0.6	0.6	0
15	30	Unbiased-30krad	0.6	0.6	0
16	35	Biased-30krad	0.6	0.6	0
17	35	Biased-30krad	0.6	0.6	0
18	35	Biased-30krad	0.6	0.6	0
19	35	Biased-30krad	0.6	0.6	0
20	35	Biased-30krad	0.6	0.6	0
30	50	Unbiased-50krad	0.6	0.6	0
31	50	Unbiased-50krad	0.6	0.6	0
32	50	Unbiased-50krad	0.6	0.6	0
33	50	Unbiased-50krad	0.6	0.6	0
34	50	Unbiased-50krad	0.6	0.6	0
40	55	Biased-50krad	0.6	0.6	0
41	55	Biased-50krad	0.6	0.6	0
42	55	Biased-50krad	0.6	0.6	0
43	55	Biased-50krad	0.6	0.6	0
44	55	Biased-50krad	0.6	0.6	0
45	100	Unbiased-100krad	0.6	0.6	0
46	100	Unbiased-100krad	0.6	0.6	0
47	100	Unbiased-100krad	0.6	0.6	0
48	100	Unbiased-100krad	0.6	0.6	0
49	100	Unbiased-100krad	0.6	0.6	0
50	105	Biased-100krad	0.6	0.6	0
51	105	Biased-100krad	0.6	0.6	0
52	105	Biased-100krad	0.6	0.6	0
53	105	Biased-100krad	0.6	0.6	0
54	105	Biased-100krad	0.6	0.6	0

Test Statistics ()

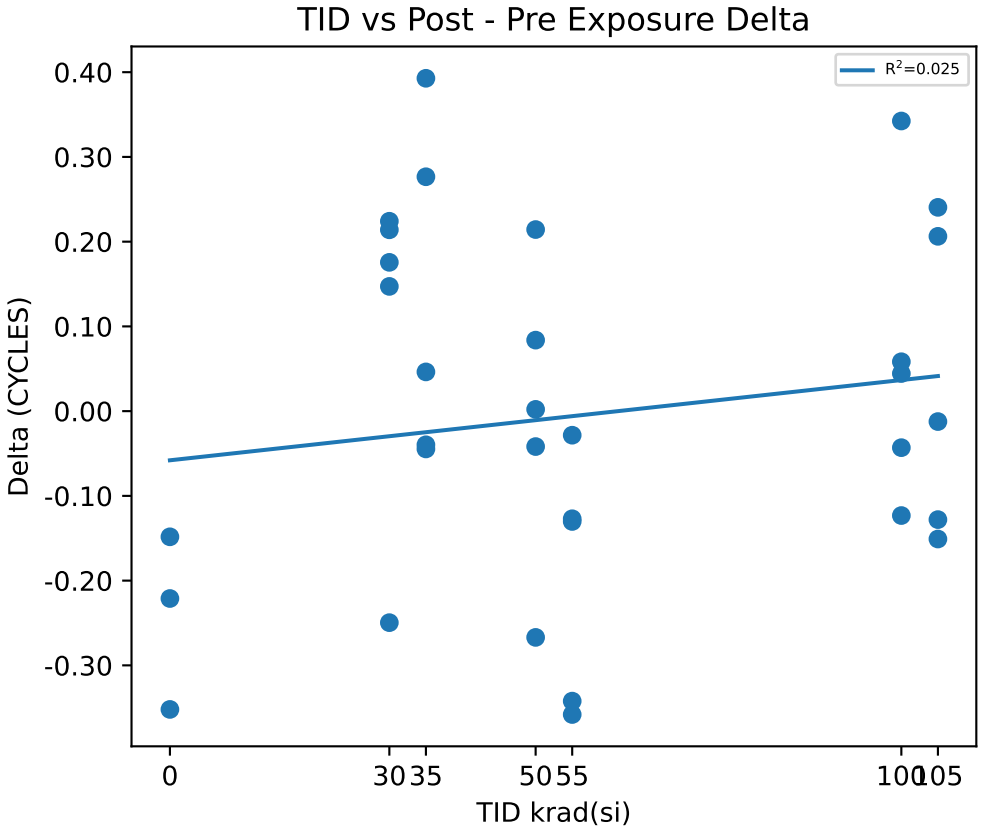
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6	0.6	0.6	0	0.6	0.6	0.6	0	0	0	0	0
30	0.6	0.6	0.6	0	0.6	0.6	0.6	0	0	0	0	0
35	0.6	0.6	0.6	0	0.6	0.6	0.6	0	0	0	0	0
50	0.6	0.6	0.6	0	0.6	0.6	0.6	0	0	0	0	0
55	0.6	0.6	0.6	0	0.6	0.6	0.6	0	0	0	0	0
100	0.6	0.6	0.6	0	0.6	0.6	0.6	0	0	0	0	0
105	0.6	0.6	0.6	0	0.6	0.6	0.6	0	0	0	0	0

Device Test: 74.22 _EXT_CLOCK|ExtToIntClkDetect/SW1/7/7//////1.8///@T_CLOCK_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.1, Upper Limit = 6.0 (CYCLES))

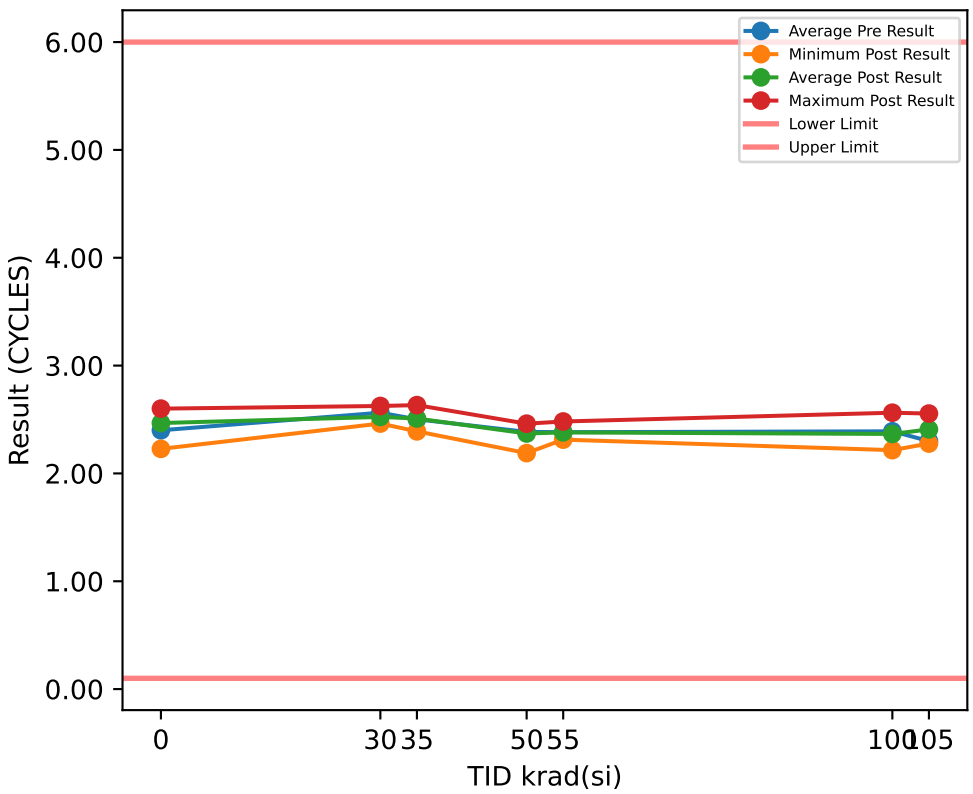
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4023	2.0503	-0.352
2	0	CU2	2.3688	2.2205	-0.1483
3	0	CU3	2.7048	2.4837	-0.2211
11	30	Unbiased-30krad	2.4082	2.6323	0.2241
12	30	Unbiased-30krad	2.4125	2.6265	0.214
13	30	Unbiased-30krad	2.6281	2.7753	0.1472
14	30	Unbiased-30krad	2.3646	2.5402	0.1756
15	30	Unbiased-30krad	2.5286	2.279	-0.2496
16	35	Biased-30krad	2.2607	2.6535	0.3928
17	35	Biased-30krad	2.5565	2.5119	-0.0446
18	35	Biased-30krad	2.568	2.6143	0.0463
19	35	Biased-30krad	2.5118	2.4721	-0.0397
20	35	Biased-30krad	2.0168	2.2934	0.2766
30	50	Unbiased-50krad	2.3048	2.3069	0.0021
31	50	Unbiased-50krad	2.5809	2.7952	0.2143
32	50	Unbiased-50krad	2.6633	2.6215	-0.0418
33	50	Unbiased-50krad	2.2656	2.3494	0.0838
34	50	Unbiased-50krad	2.512	2.245	-0.267
40	55	Biased-50krad	2.4594	2.431	-0.0284
41	55	Biased-50krad	2.3305	2.2035	-0.127
42	55	Biased-50krad	2.6583	2.3003	-0.358
43	55	Biased-50krad	2.527	2.3968	-0.1302
44	55	Biased-50krad	2.7103	2.3681	-0.3422
45	100	Unbiased-100krad	2.4669	2.8093	0.3424
46	100	Unbiased-100krad	2.4055	2.4638	0.0583
47	100	Unbiased-100krad	2.3602	2.4046	0.0444
48	100	Unbiased-100krad	2.5008	2.4577	-0.0431
49	100	Unbiased-100krad	2.7533	2.6301	-0.1232
50	105	Biased-100krad	2.2348	2.4753	0.2405
51	105	Biased-100krad	2.2341	2.1061	-0.128
52	105	Biased-100krad	2.3024	2.2901	-0.0123
53	105	Biased-100krad	2.2753	2.4816	0.2063
54	105	Biased-100krad	2.5586	2.4077	-0.1509

Test Statistics (CYCLES)

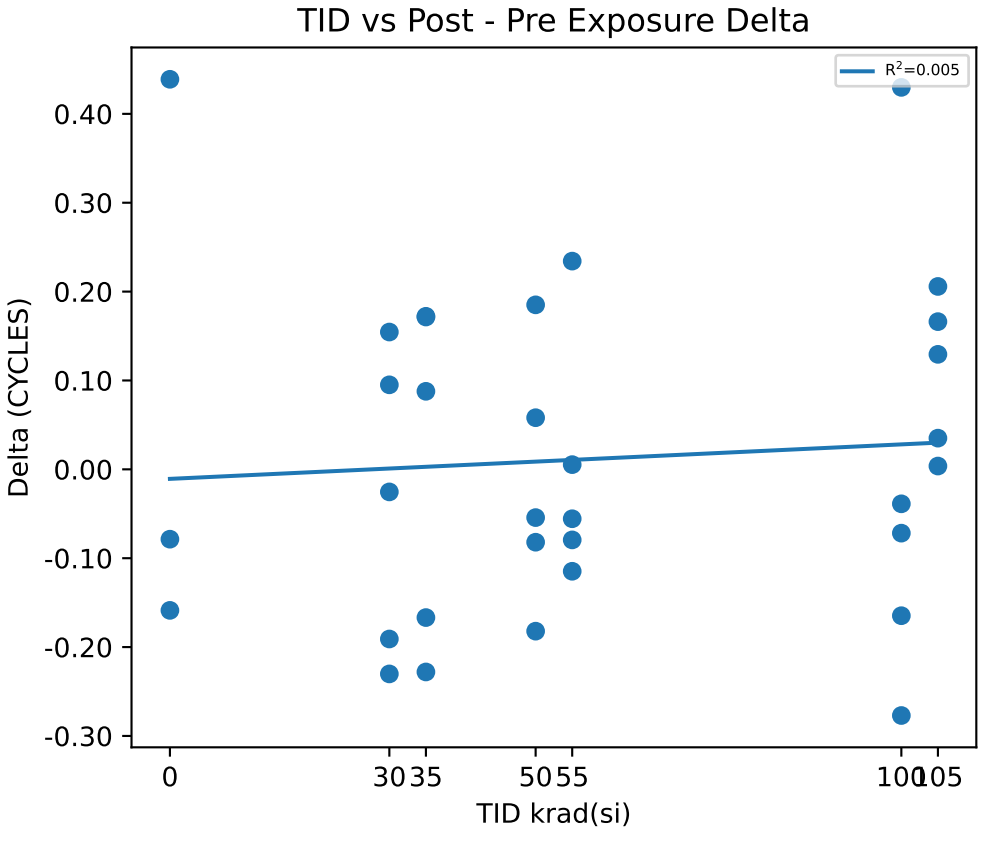
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3688	2.492	2.7048	0.18508	2.0503	2.2515	2.4837	0.21836	-0.352	-0.24047	-0.1483	0.10322
30	2.3646	2.4684	2.6281	0.10799	2.279	2.5707	2.7753	0.18357	-0.2496	0.10226	0.2241	0.19908
35	2.0168	2.3828	2.568	0.23978	2.2934	2.509	2.6535	0.14126	-0.0446	0.12628	0.3928	0.19797
50	2.2656	2.4653	2.6633	0.17349	2.245	2.4636	2.7952	0.23467	-0.267	-0.00172	0.2143	0.17746
55	2.3305	2.5371	2.7103	0.1529	2.2035	2.3399	2.431	0.090146	-0.358	-0.19716	-0.0284	0.1456
100	2.3602	2.4973	2.7533	0.15305	2.4046	2.5531	2.8093	0.16635	-0.1232	0.05576	0.3424	0.17614
105	2.2341	2.321	2.5586	0.1359	2.1061	2.3522	2.4816	0.15764	-0.1509	0.03112	0.2405	0.18362

Device Test: 74.23 _EXT_CLOCK|ExtToIntClkDetect/SW2/7/7//////1.8///@T_CLOCK_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.1, Upper Limit = 6.0 (CYCLES))

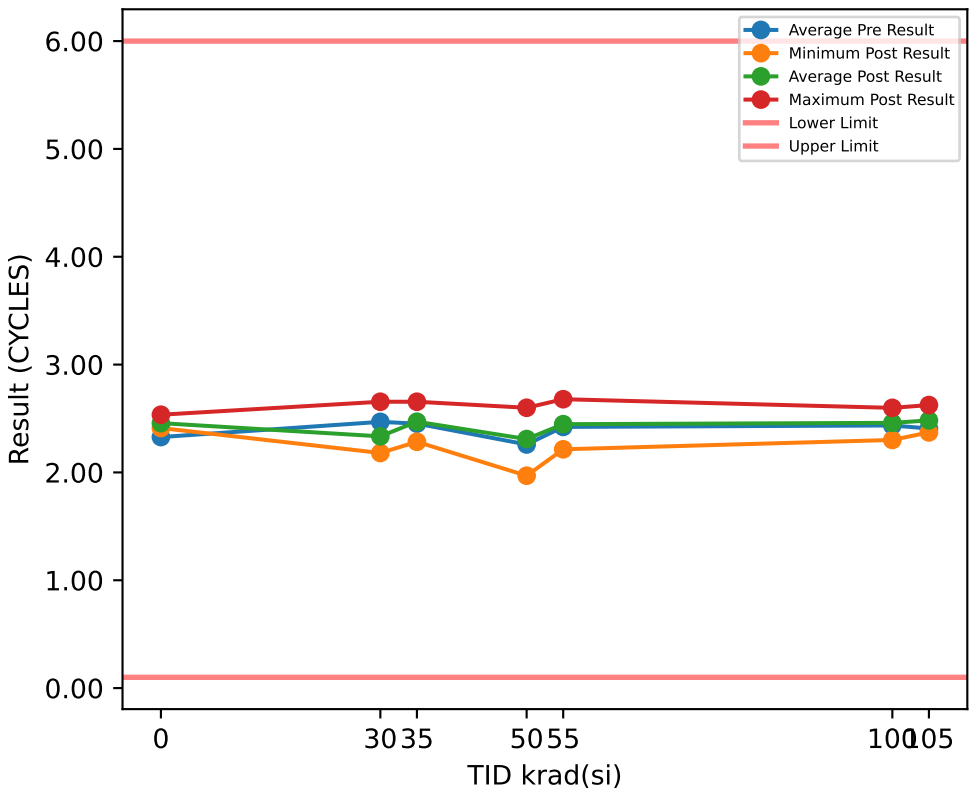
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3865	2.2278	-0.1587
2	0	CU2	2.6794	2.6008	-0.0786
3	0	CU3	2.1342	2.5731	0.4389
11	30	Unbiased-30krad	2.7336	2.5034	-0.2302
12	30	Unbiased-30krad	2.7189	2.528	-0.1909
13	30	Unbiased-30krad	2.3449	2.4994	0.1545
14	30	Unbiased-30krad	2.5303	2.6254	0.0951
15	30	Unbiased-30krad	2.4878	2.4624	-0.0254
16	35	Biased-30krad	2.4612	2.6334	0.1722
17	35	Biased-30krad	2.6309	2.4641	-0.1668
18	35	Biased-30krad	2.3444	2.5158	0.1714
19	35	Biased-30krad	2.4551	2.5429	0.0878
20	35	Biased-30krad	2.6181	2.3901	-0.228
30	50	Unbiased-50krad	2.3195	2.3776	0.0581
31	50	Unbiased-50krad	2.5499	2.3678	-0.1821
32	50	Unbiased-50krad	2.2762	2.4613	0.1851
33	50	Unbiased-50krad	2.2429	2.1886	-0.0543
34	50	Unbiased-50krad	2.5377	2.4557	-0.082
40	55	Biased-50krad	2.4041	2.3485	-0.0556
41	55	Biased-50krad	2.2473	2.4816	0.2343
42	55	Biased-50krad	2.4502	2.3355	-0.1147
43	55	Biased-50krad	2.4177	2.423	0.0053
44	55	Biased-50krad	2.3929	2.3135	-0.0794
45	100	Unbiased-100krad	2.5172	2.3525	-0.1647
46	100	Unbiased-100krad	2.4105	2.3387	-0.0718
47	100	Unbiased-100krad	2.3986	2.3598	-0.0388
48	100	Unbiased-100krad	2.4929	2.2159	-0.277
49	100	Unbiased-100krad	2.1332	2.563	0.4298
50	105	Biased-100krad	2.314	2.3491	0.0351
51	105	Biased-100krad	2.3395	2.5057	0.1662
52	105	Biased-100krad	2.1489	2.3547	0.2058
53	105	Biased-100krad	2.5514	2.5551	0.0037
54	105	Biased-100krad	2.1476	2.277	0.1294

Test Statistics (CYCLES)

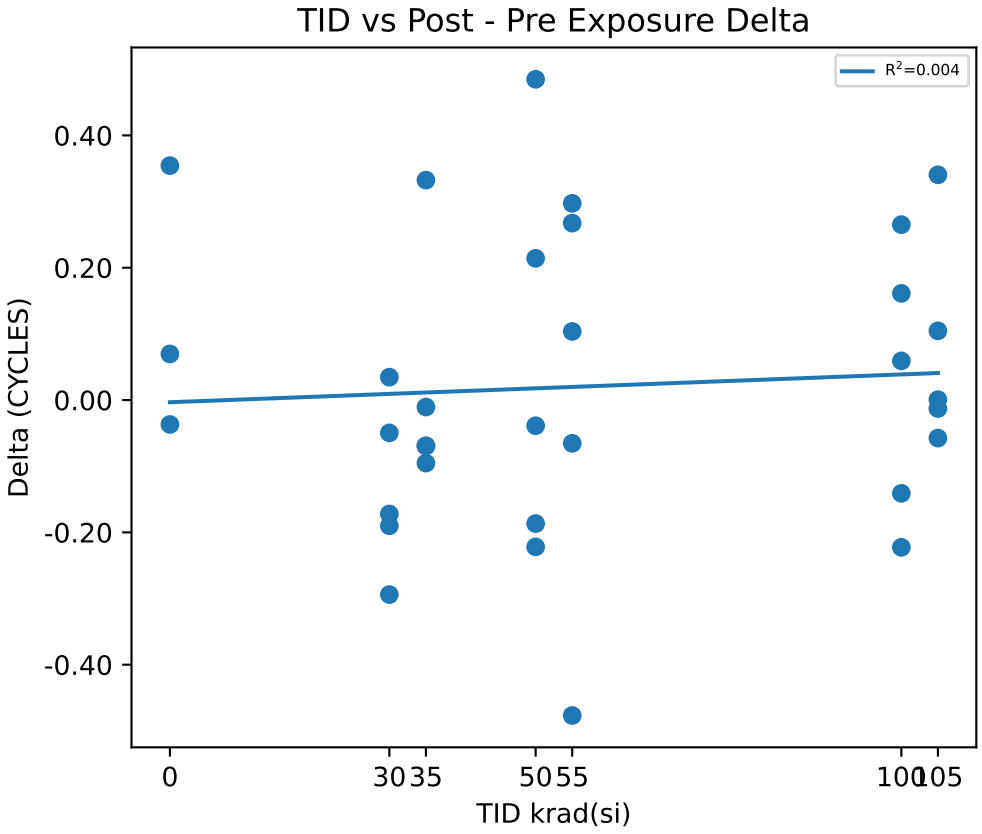
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1342	2.4	2.6794	0.27285	2.2278	2.4672	2.6008	0.20782	-0.1587	0.0672	0.4389	0.32438
30	2.3449	2.5631	2.7336	0.16409	2.4624	2.5237	2.6254	0.061485	-0.2302	-0.03938	0.1545	0.16974
35	2.3444	2.5019	2.6309	0.12124	2.3901	2.5093	2.6334	0.090587	-0.228	0.00732	0.1722	0.19123
50	2.2429	2.3852	2.5499	0.14733	2.1886	2.3702	2.4613	0.11028	-0.1821	-0.01504	0.1851	0.14084
55	2.2473	2.3824	2.4502	0.078543	2.3135	2.3804	2.4816	0.069938	-0.1147	-0.00202	0.2343	0.13915
100	2.1332	2.3905	2.5172	0.15265	2.2159	2.366	2.563	0.1248	-0.277	-0.0245	0.4298	0.2703
105	2.1476	2.3003	2.5514	0.16659	2.277	2.4083	2.5551	0.11689	0.0037	0.10804	0.2058	0.086028

Device Test: 74.24 _EXT_CLOCK|ExtToIntClkDetect/SW3/7/7/////1.8///@T_CLOCK_DET

TID vs Result Stats



TID vs Post - Pre Exposure Delta



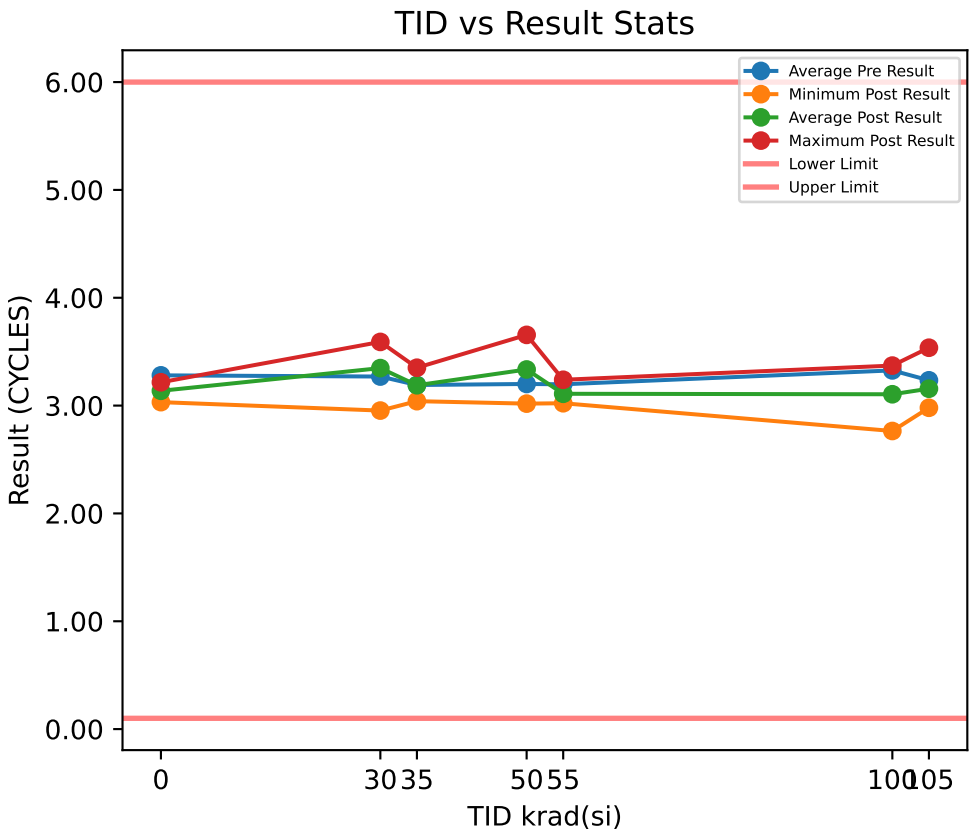
Test Results (Lower Limit = 0.1, Upper Limit = 6.0 (CYCLES))

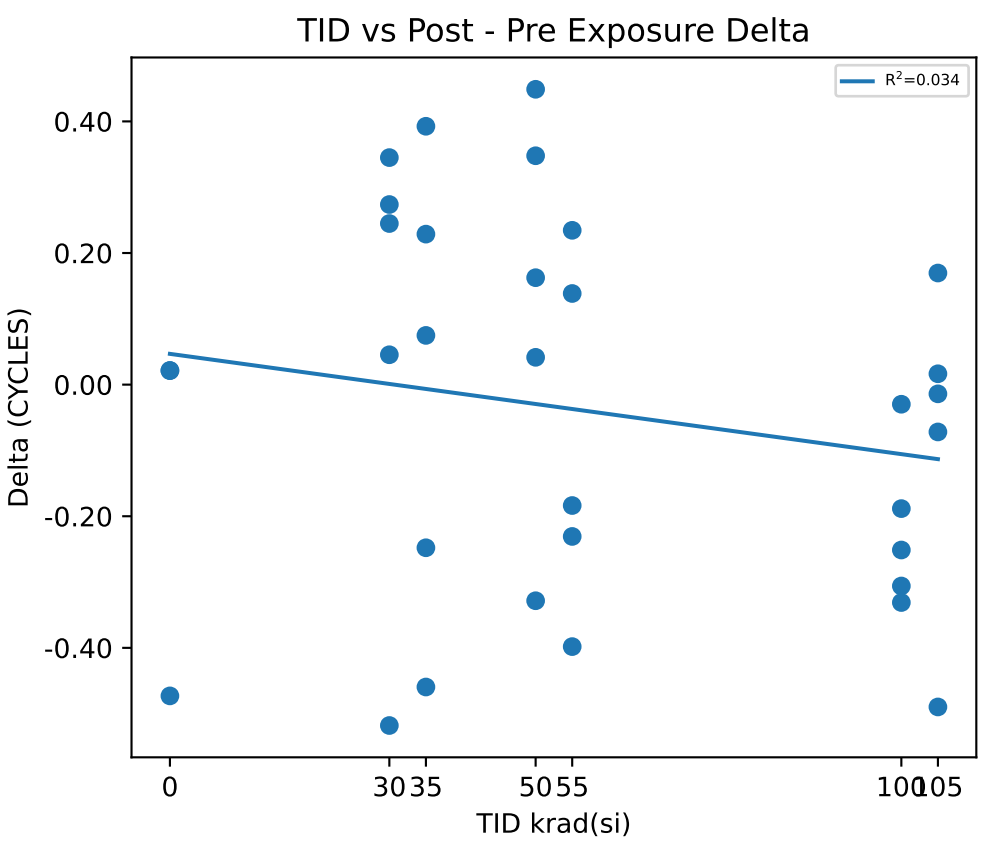
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1808	2.5351	0.3543
2	0	CU2	2.3548	2.4245	0.0697
3	0	CU3	2.4485	2.4116	-0.0369
11	30	Unbiased-30krad	2.5368	2.2428	-0.294
12	30	Unbiased-30krad	2.7051	2.6555	-0.0496
13	30	Unbiased-30krad	2.3704	2.1804	-0.19
14	30	Unbiased-30krad	2.3379	2.3725	0.0346
15	30	Unbiased-30krad	2.3941	2.2219	-0.1722
16	35	Biased-30krad	2.3534	2.2841	-0.0693
17	35	Biased-30krad	2.6104	2.5998	-0.0106
18	35	Biased-30krad	2.401	2.3317	-0.0693
19	35	Biased-30krad	2.323	2.6554	0.3324
20	35	Biased-30krad	2.5754	2.4801	-0.0953
30	50	Unbiased-50krad	2.2807	2.094	-0.1867
31	50	Unbiased-50krad	2.6673	2.4454	-0.2219
32	50	Unbiased-50krad	1.9538	2.4386	0.4848
33	50	Unbiased-50krad	2.0084	1.9696	-0.0388
34	50	Unbiased-50krad	2.3854	2.5996	0.2142
40	55	Biased-50krad	2.5651	2.4997	-0.0654
41	55	Biased-50krad	2.3284	2.4321	0.1037
42	55	Biased-50krad	2.6911	2.2143	-0.4768
43	55	Biased-50krad	2.4116	2.679	0.2674
44	55	Biased-50krad	2.1142	2.4115	0.2973
45	100	Unbiased-100krad	2.3336	2.5987	0.2651
46	100	Unbiased-100krad	2.3419	2.5031	0.1612
47	100	Unbiased-100krad	2.4677	2.5269	0.0592
48	100	Unbiased-100krad	2.51	2.369	-0.141
49	100	Unbiased-100krad	2.5237	2.3011	-0.2226
50	105	Biased-100krad	2.384	2.3712	-0.0128
51	105	Biased-100krad	2.5023	2.4448	-0.0575
52	105	Biased-100krad	2.2362	2.5766	0.3404
53	105	Biased-100krad	2.6241	2.6247	0.0006
54	105	Biased-100krad	2.2899	2.3945	0.1046

Test Statistics (CYCLES)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1808	2.328	2.4485	0.13584	2.4116	2.4571	2.5351	0.067886	-0.0369	0.12903	0.3543	0.20224
30	2.3379	2.4689	2.7051	0.15236	2.1804	2.3346	2.6555	0.19321	-0.294	-0.13424	0.0346	0.1282
35	2.323	2.4526	2.6104	0.13161	2.2841	2.4702	2.6554	0.16203	-0.0953	0.01758	0.3324	0.17871
50	1.9538	2.2591	2.6673	0.29116	1.9696	2.3094	2.5996	0.26517	-0.2219	0.05032	0.4848	0.29743
55	2.1142	2.4221	2.6911	0.22164	2.2143	2.4473	2.679	0.16751	-0.4768	0.02524	0.2973	0.31586
100	2.3336	2.4354	2.5237	0.09153	2.3011	2.4598	2.5987	0.12155	-0.2226	0.02438	0.2651	0.20386
105	2.2362	2.4073	2.6241	0.15782	2.3712	2.4824	2.6247	0.1125	-0.0575	0.07506	0.3404	0.15978

Device Test: 74.25 _EXT_CLOCK|ExtToIntClkDetect/SW4/7/7/////1.8///@T_CLOCK_DET





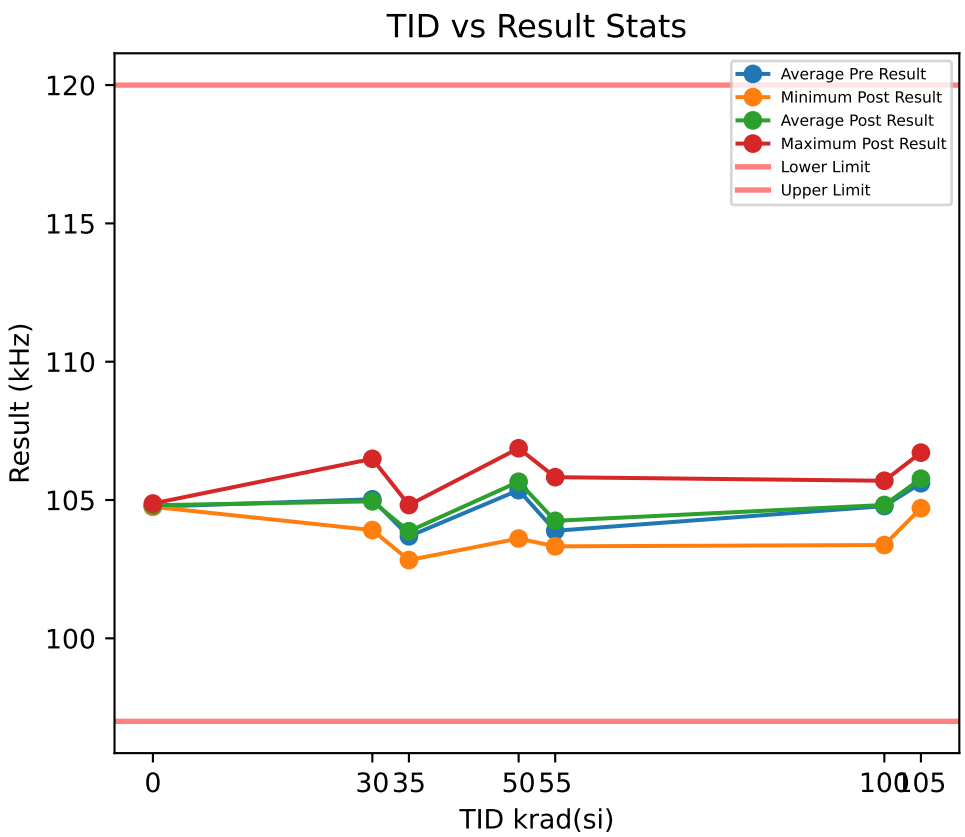
Test Results (Lower Limit = 0.1, Upper Limit = 6.0 (CYCLES))

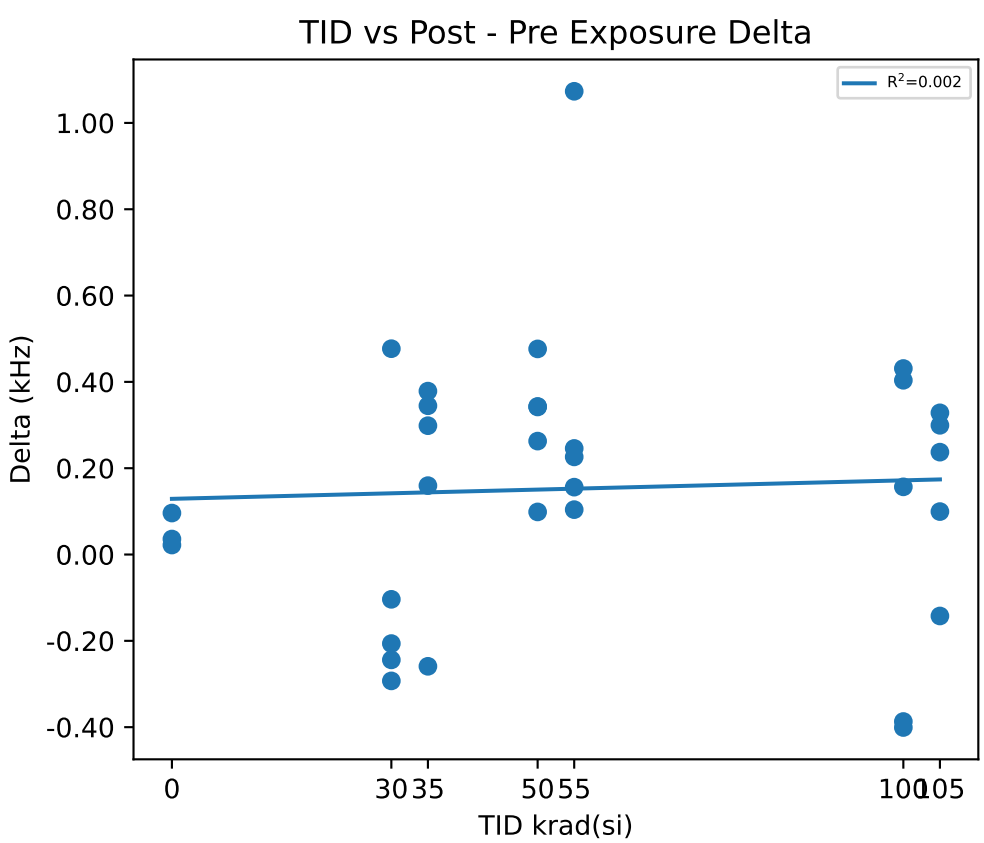
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.1949	3.2162	0.0213
2	0	CU2	3.0105	3.032	0.0215
3	0	CU3	3.6361	3.1631	-0.473
11	30	Unbiased-30krad	3.2454	3.5904	0.345
12	30	Unbiased-30krad	3.1002	3.3739	0.2737
13	30	Unbiased-30krad	3.2447	3.4895	0.2448
14	30	Unbiased-30krad	3.4718	2.9538	-0.518
15	30	Unbiased-30krad	3.2848	3.3302	0.0454
16	35	Biased-30krad	3.182	3.2568	0.0748
17	35	Biased-30krad	3.015	3.2437	0.2287
18	35	Biased-30krad	3.5005	3.041	-0.4595
19	35	Biased-30krad	2.9585	3.3511	0.3926
20	35	Biased-30krad	3.2982	3.0503	-0.2479
30	50	Unbiased-50krad	3.2069	3.6557	0.4488
31	50	Unbiased-50krad	3.4171	3.5796	0.1625
32	50	Unbiased-50krad	3.4207	3.0923	-0.3284
33	50	Unbiased-50krad	2.9767	3.0182	0.0415
34	50	Unbiased-50krad	2.9809	3.3287	0.3478
40	55	Biased-50krad	3.3724	3.1417	-0.2307
41	55	Biased-50krad	2.9674	3.1059	0.1385
42	55	Biased-50krad	3.0049	3.2394	0.2345
43	55	Biased-50krad	3.4199	3.0218	-0.3981
44	55	Biased-50krad	3.2225	3.0388	-0.1837
45	100	Unbiased-100krad	3.0704	2.7644	-0.306
46	100	Unbiased-100krad	3.4008	3.371	-0.0298
47	100	Unbiased-100krad	3.6362	3.3051	-0.3311
48	100	Unbiased-100krad	3.195	2.9437	-0.2513
49	100	Unbiased-100krad	3.3293	3.1409	-0.1884
50	105	Biased-100krad	3.0826	3.0991	0.0165
51	105	Biased-100krad	3.4696	2.9798	-0.4898
52	105	Biased-100krad	3.5506	3.5366	-0.014
53	105	Biased-100krad	3.0834	3.0115	-0.0719
54	105	Biased-100krad	2.9862	3.1558	0.1696

Test Statistics (CYCLES)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.0105	3.2805	3.6361	0.32146	3.032	3.1371	3.2162	0.094812	-0.473	-0.1434	0.0215	0.28544
30	3.1002	3.2694	3.4718	0.13325	2.9538	3.3476	3.5904	0.24247	-0.518	0.07818	0.345	0.35131
35	2.9585	3.1908	3.5005	0.21931	3.041	3.1886	3.3511	0.13694	-0.4595	-0.00226	0.3926	0.34807
50	2.9767	3.2005	3.4207	0.22009	3.0182	3.3349	3.6557	0.28372	-0.3284	0.13444	0.4488	0.30331
55	2.9674	3.1974	3.4199	0.20659	3.0218	3.1095	3.2394	0.087484	-0.3981	-0.0879	0.2345	0.26504
100	3.0704	3.3263	3.6362	0.21466	2.7644	3.105	3.371	0.25205	-0.3311	-0.22132	-0.0298	0.1203
105	2.9862	3.2345	3.5506	0.2563	2.9798	3.1566	3.5366	0.22362	-0.4898	-0.07792	0.1696	0.24696

Device Test: 75.2 _IntFreq|Freq/RT_511/7/7///90.9/634//1.8///@EXT_SET_FREQ_100KHZ





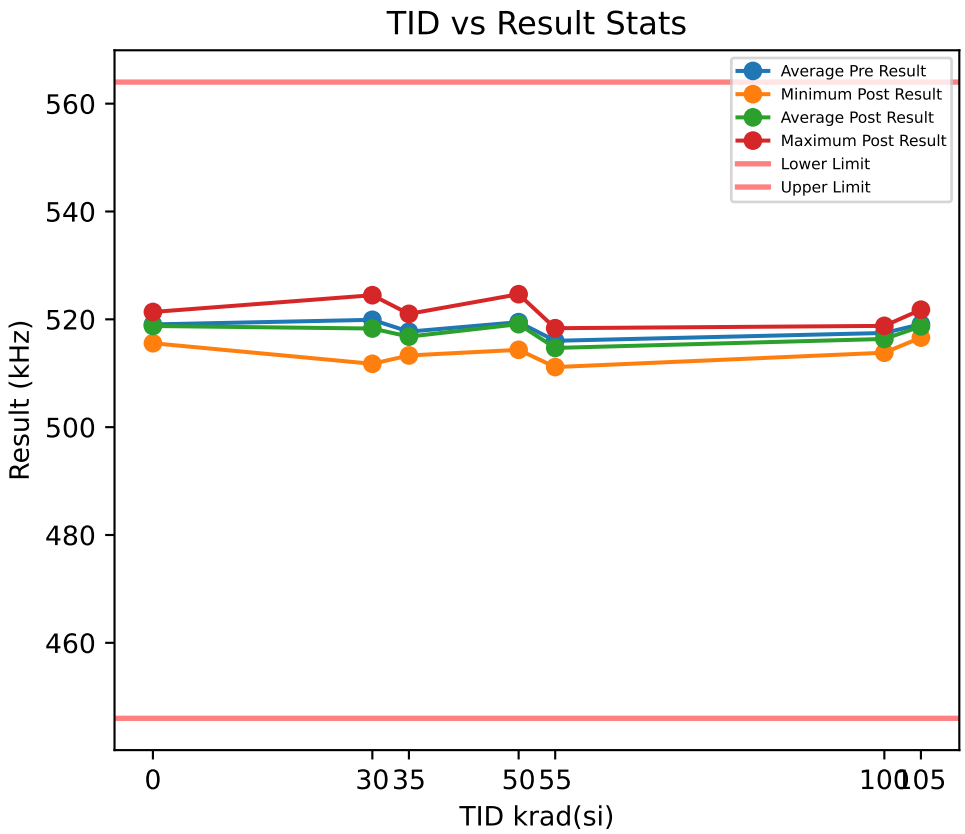
Test Results (Lower Limit = 97.0, Upper Limit = 120.0 (kHz))

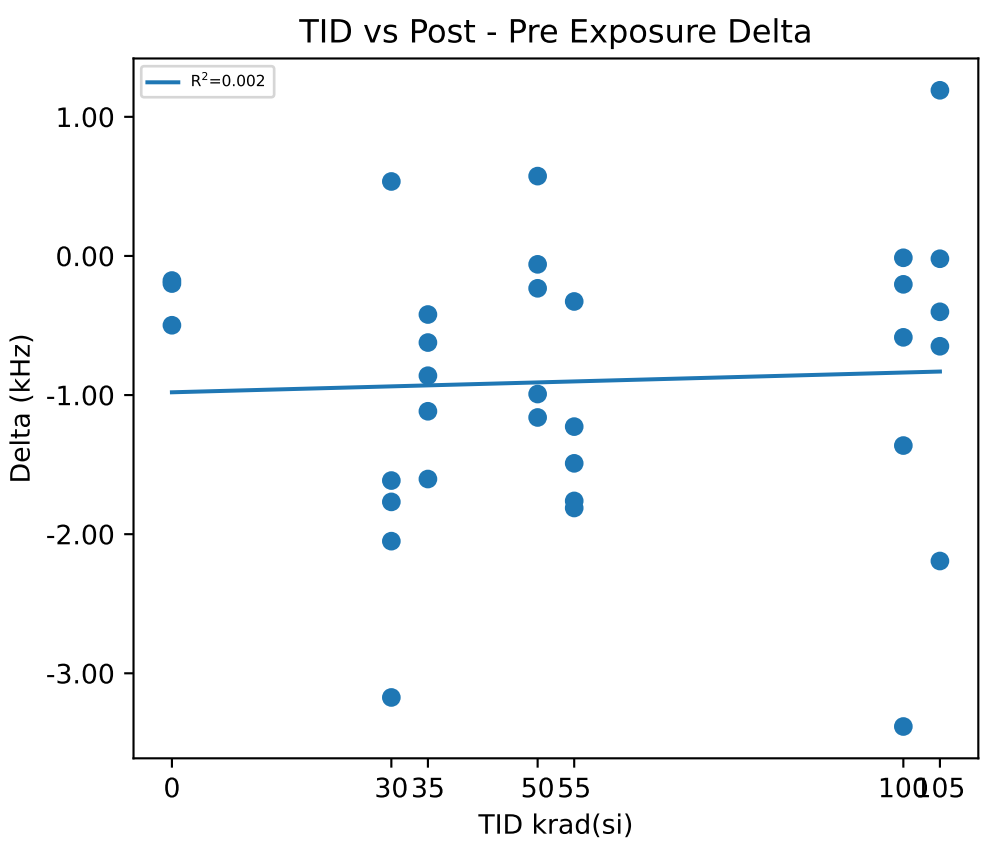
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	104.84	104.87	0.0359
2	0	CU2	104.66	104.75	0.0961
3	0	CU3	104.78	104.8	0.022
11	30	Unbiased-30krad	104.24	104.03	-0.2063
12	30	Unbiased-30krad	104.21	103.91	-0.2928
13	30	Unbiased-30krad	104.6	105.08	0.4769
14	30	Unbiased-30krad	105.35	105.24	-0.1038
15	30	Unbiased-30krad	106.73	106.49	-0.2441
16	35	Biased-30krad	104.44	104.82	0.3786
17	35	Biased-30krad	102.48	102.83	0.3447
18	35	Biased-30krad	104.49	104.79	0.2985
19	35	Biased-30krad	104.02	103.76	-0.259
20	35	Biased-30krad	103	103.16	0.1596
30	50	Unbiased-50krad	105.45	105.55	0.0987
31	50	Unbiased-50krad	103.26	103.61	0.3431
32	50	Unbiased-50krad	105.56	106.03	0.4764
33	50	Unbiased-50krad	106.61	106.87	0.2628
34	50	Unbiased-50krad	105.9	106.24	0.3419
40	55	Biased-50krad	103.22	103.33	0.104
41	55	Biased-50krad	104.75	105.83	1.0733
42	55	Biased-50krad	103.85	104.01	0.1561
43	55	Biased-50krad	104.11	104.35	0.2458
44	55	Biased-50krad	103.5	103.73	0.2262
45	100	Unbiased-100krad	104.32	104.73	0.4037
46	100	Unbiased-100krad	105.4	105.55	0.1568
47	100	Unbiased-100krad	103.76	103.37	-0.3869
48	100	Unbiased-100krad	105.16	104.76	-0.4008
49	100	Unbiased-100krad	105.26	105.7	0.431
50	105	Biased-100krad	106.16	106.49	0.3283
51	105	Biased-100krad	105.31	105.41	0.0995
52	105	Biased-100krad	106.86	106.71	-0.1424
53	105	Biased-100krad	104.47	104.7	0.2372
54	105	Biased-100krad	105.23	105.53	0.2994

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	104.66	104.76	104.84	0.091499	104.75	104.81	104.87	0.060214	0.022	0.051333	0.0961	0.039387
30	104.21	105.03	106.73	1.0593	103.91	104.95	106.49	1.0474	-0.2928	-0.07402	0.4769	0.31571
35	102.48	103.69	104.49	0.90146	102.83	103.87	104.82	0.91572	-0.259	0.18448	0.3786	0.26156
50	103.26	105.36	106.61	1.2542	103.61	105.66	106.87	1.2423	0.0987	0.30458	0.4764	0.13832
55	103.22	103.89	104.75	0.5888	103.33	104.25	105.83	0.95859	0.104	0.36108	1.0733	0.40213
100	103.76	104.78	105.4	0.70855	103.37	104.82	105.7	0.92391	-0.4008	0.04076	0.431	0.4109
105	104.47	105.61	106.86	0.92025	104.7	105.77	106.71	0.82503	-0.1424	0.1644	0.3283	0.19283

Device Test: 75.3 _IntFreq|Freq/RT_90P9/7/7///90.9/634//1.8///@EXT_SET_FREQ_500KHZ





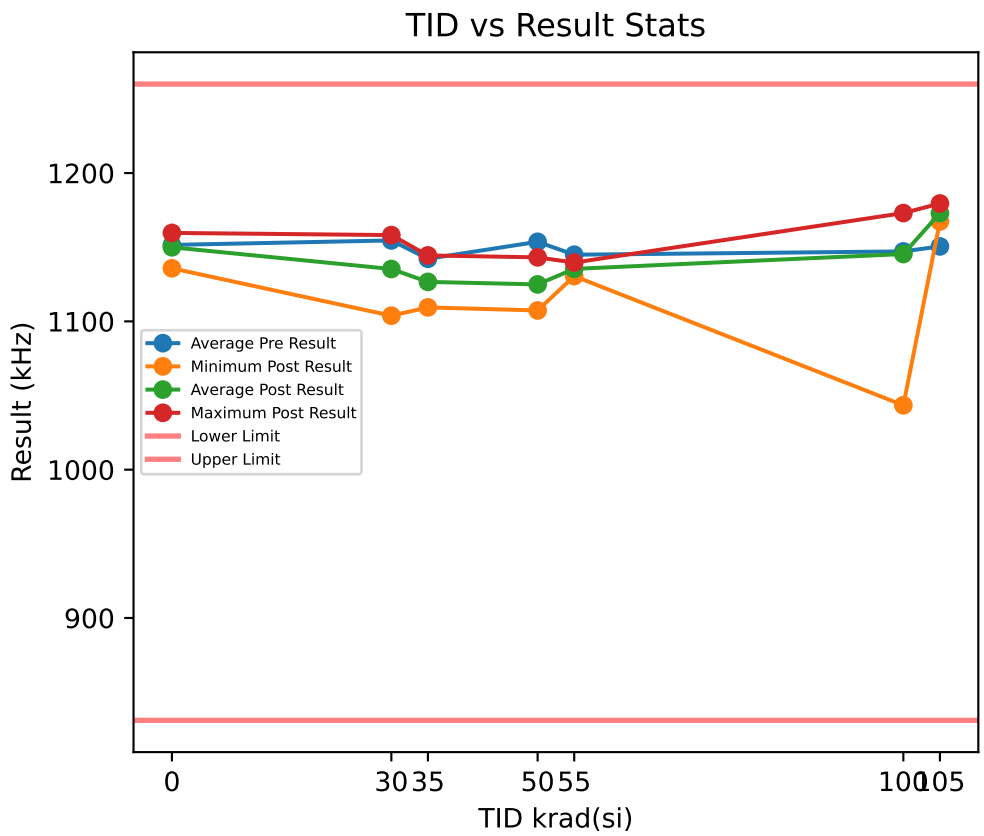
Test Results (Lower Limit = 446.0, Upper Limit = 564.0 (kHz))

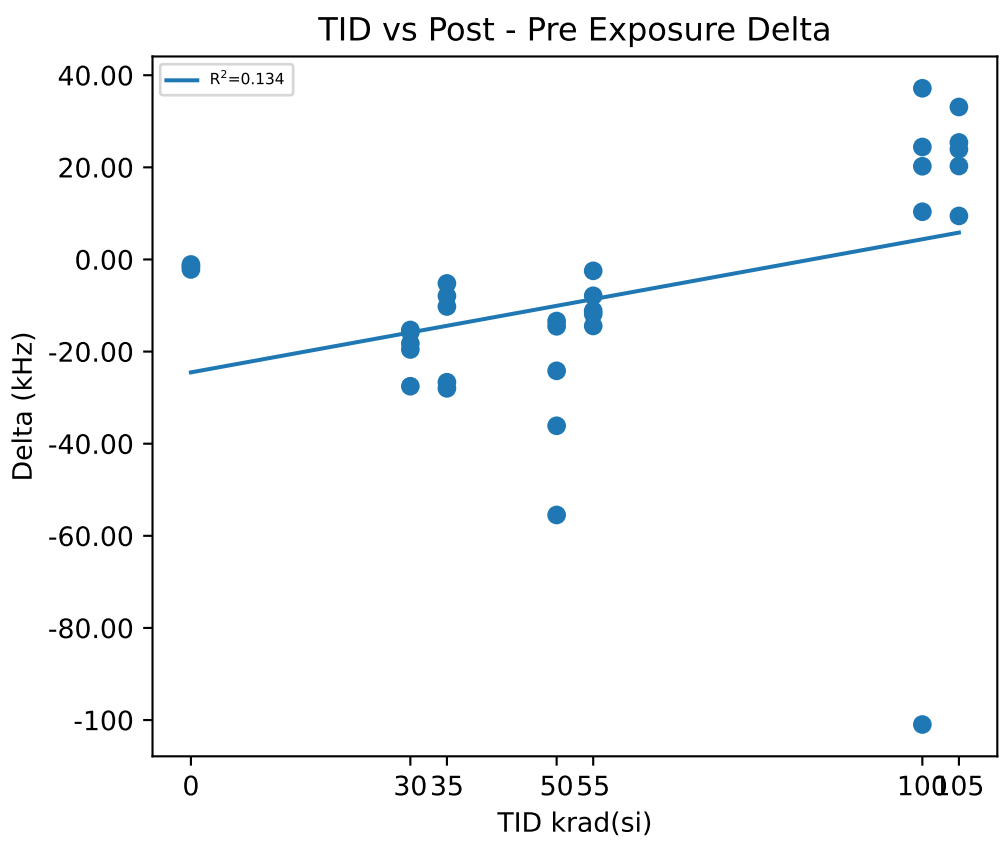
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	521.86	521.36	-0.4982
2	0	CU2	515.74	515.57	-0.1767
3	0	CU3	519.55	519.36	-0.1985
11	30	Unbiased-30krad	514.92	511.75	-3.1737
12	30	Unbiased-30krad	520.19	518.57	-1.6145
13	30	Unbiased-30krad	520	520.54	0.5354
14	30	Unbiased-30krad	517.91	516.14	-1.7679
15	30	Unbiased-30krad	526.52	524.47	-2.0502
16	35	Biased-30krad	520.91	520.28	-0.6225
17	35	Biased-30krad	514.16	513.3	-0.8609
18	35	Biased-30krad	522.13	521.01	-1.1165
19	35	Biased-30krad	517.49	515.89	-1.6035
20	35	Biased-30krad	513.9	513.48	-0.421
30	50	Unbiased-50krad	518.12	517.89	-0.2326
31	50	Unbiased-50krad	513.77	514.34	0.5739
32	50	Unbiased-50krad	519.15	519.09	-0.0603
33	50	Unbiased-50krad	525.82	524.66	-1.1611
34	50	Unbiased-50krad	520.53	519.54	-0.9926
40	55	Biased-50krad	512.9	511.14	-1.761
41	55	Biased-50krad	518.63	518.3	-0.3272
42	55	Biased-50krad	520.17	518.35	-1.8117
43	55	Biased-50krad	514.27	512.78	-1.4908
44	55	Biased-50krad	514.12	512.89	-1.2268
45	100	Unbiased-100krad	515.91	515.89	-0.0132
46	100	Unbiased-100krad	517.99	517.4	-0.5851
47	100	Unbiased-100krad	515.17	513.81	-1.3629
48	100	Unbiased-100krad	519.29	515.91	-3.3825
49	100	Unbiased-100krad	518.99	518.78	-0.2041
50	105	Biased-100krad	521.15	520.51	-0.6492
51	105	Biased-100krad	517.7	517.68	-0.0201
52	105	Biased-100krad	522.19	521.78	-0.4015
53	105	Biased-100krad	518.8	516.61	-2.1929
54	105	Biased-100krad	515.65	516.85	1.1908

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	515.74	519.05	521.86	3.0887	515.57	518.76	521.36	2.9425	-0.4982	-0.29113	-0.1767	0.17966
30	514.92	519.91	526.52	4.2624	511.75	518.29	524.47	4.7626	-3.1737	-1.6142	0.5354	1.3478
35	513.9	517.72	522.13	3.7724	513.3	516.79	521.01	3.6746	-1.6035	-0.92488	-0.421	0.46007
50	513.77	519.48	525.82	4.3548	514.34	519.1	524.66	3.7141	-1.1611	-0.37454	0.5739	0.71048
55	512.9	516.02	520.17	3.1759	511.14	514.69	518.35	3.3872	-1.8117	-1.3235	-0.3272	0.60409
100	515.17	517.47	519.29	1.8457	513.81	516.36	518.78	1.8634	-3.3825	-1.1096	-0.0132	1.3718
105	515.65	519.1	522.19	2.6295	516.61	518.69	521.78	2.3248	-2.1929	-0.41458	1.1908	1.2197

Device Test: 75.4 _IntFreq|Freq/RT37P4/7/7///90.9/634//1.8///@EXT_SET_FREQ_1000KHZ





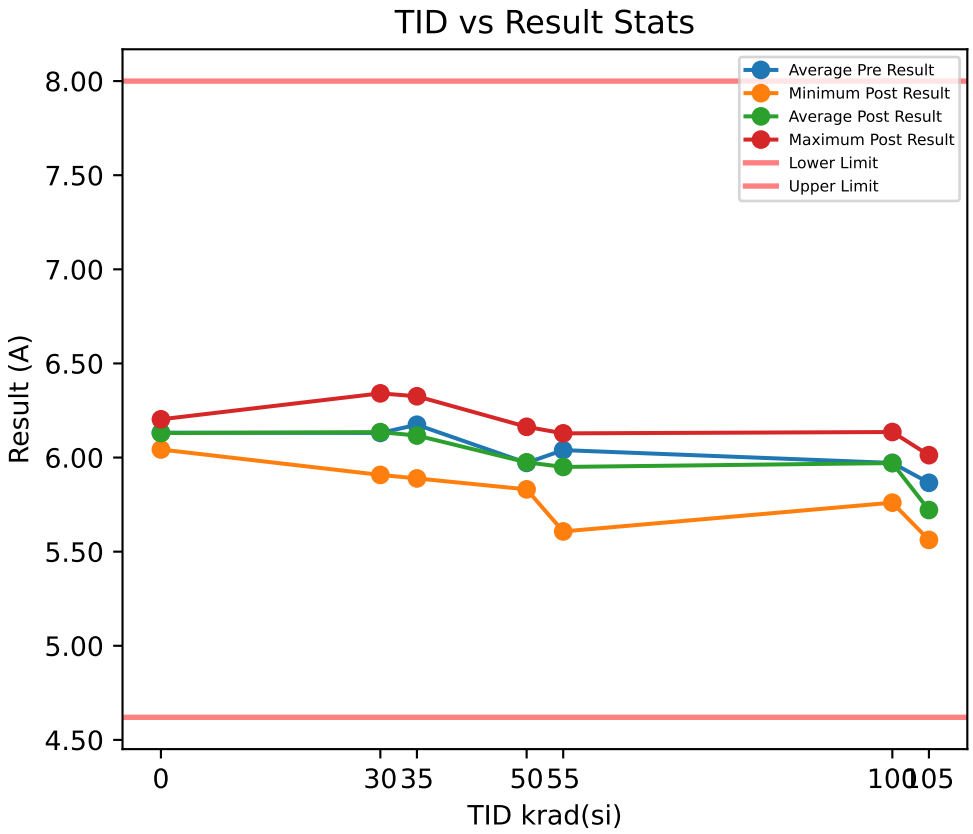
Test Results (Lower Limit = 831.0, Upper Limit = 1260.0 (kHz))

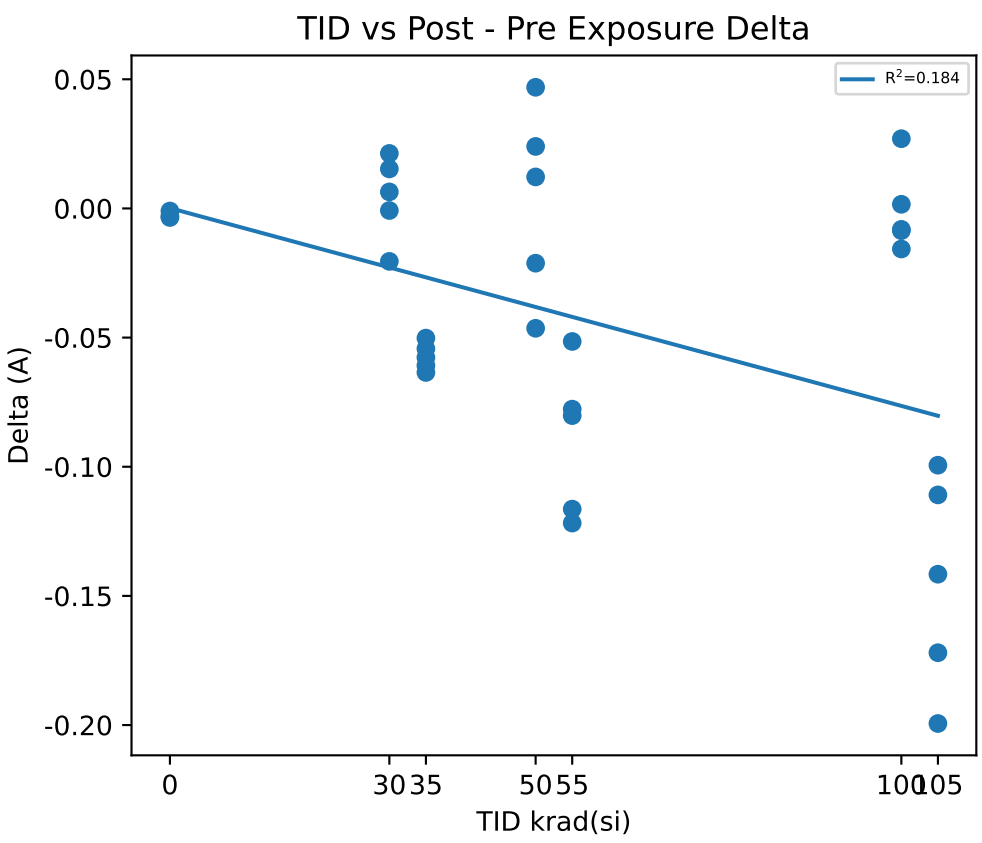
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1156.6	1154.4	-2.1672
2	0	CU2	1136.9	1135.8	-1.0868
3	0	CU3	1161.2	1159.6	-1.5204
11	30	Unbiased-30krad	1131.4	1103.8	-27.522
12	30	Unbiased-30krad	1159.4	1141.2	-18.24
13	30	Unbiased-30krad	1157	1141.2	-15.759
14	30	Unbiased-30krad	1151.7	1132.1	-19.551
15	30	Unbiased-30krad	1173.5	1158.2	-15.306
16	35	Biased-30krad	1142.5	1137.3	-5.1993
17	35	Biased-30krad	1132.1	1124.2	-7.9206
18	35	Biased-30krad	1154.7	1144.5	-10.216
19	35	Biased-30krad	1145.7	1117.7	-27.98
20	35	Biased-30krad	1136.1	1109.4	-26.649
30	50	Unbiased-50krad	1154.8	1141.4	-13.365
31	50	Unbiased-50krad	1143.5	1107.4	-36.112
32	50	Unbiased-50krad	1137.9	1113.7	-24.178
33	50	Unbiased-50krad	1157.7	1143.2	-14.514
34	50	Unbiased-50krad	1174.4	1119	-55.473
40	55	Biased-50krad	1145	1130.5	-14.437
41	55	Biased-50krad	1150.8	1139.6	-11.139
42	55	Biased-50krad	1148.2	1136.3	-11.849
43	55	Biased-50krad	1135.5	1133.1	-2.4714
44	55	Biased-50krad	1145.3	1137.4	-7.8833
45	100	Unbiased-100krad	1144.4	1043.4	-100.97
46	100	Unbiased-100krad	1146.8	1171.2	24.421
47	100	Unbiased-100krad	1148.2	1168.4	20.234
48	100	Unbiased-100krad	1160.6	1171	10.36
49	100	Unbiased-100krad	1135.9	1173	37.163
50	105	Biased-100krad	1161.7	1171.2	9.4496
51	105	Biased-100krad	1149.2	1174.6	25.401
52	105	Biased-100krad	1146.4	1179.5	33.101
53	105	Biased-100krad	1151.9	1172.2	20.286
54	105	Biased-100krad	1143.4	1167.3	23.928

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1136.9	1151.5	1161.2	12.902	1135.8	1150	1159.6	12.535	-2.1672	-1.5915	-1.0868	0.54369
30	1131.4	1154.6	1173.5	15.288	1103.8	1135.3	1158.2	19.963	-27.522	-19.276	-15.306	4.9313
35	1132.1	1142.2	1154.7	8.7576	1109.4	1126.6	1144.5	14.251	-27.98	-15.593	-5.1993	10.857
50	1137.9	1153.6	1174.4	14.156	1107.4	1124.9	1143.2	16.385	-55.473	-28.728	-13.365	17.526
55	1135.5	1144.9	1150.8	5.7693	1130.5	1135.4	1139.6	3.6102	-14.437	-9.5558	-2.4714	4.5982
100	1135.9	1147.2	1160.6	8.9105	1043.4	1145.4	1173	57.044	-100.97	-1.7578	37.163	56.287
105	1143.4	1150.5	1161.7	7.0163	1167.3	1173	1179.5	4.4867	9.4496	22.433	33.101	8.6317

Device Test: 77.2 _ILIM_LS|LS_Sourcing/SW1/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





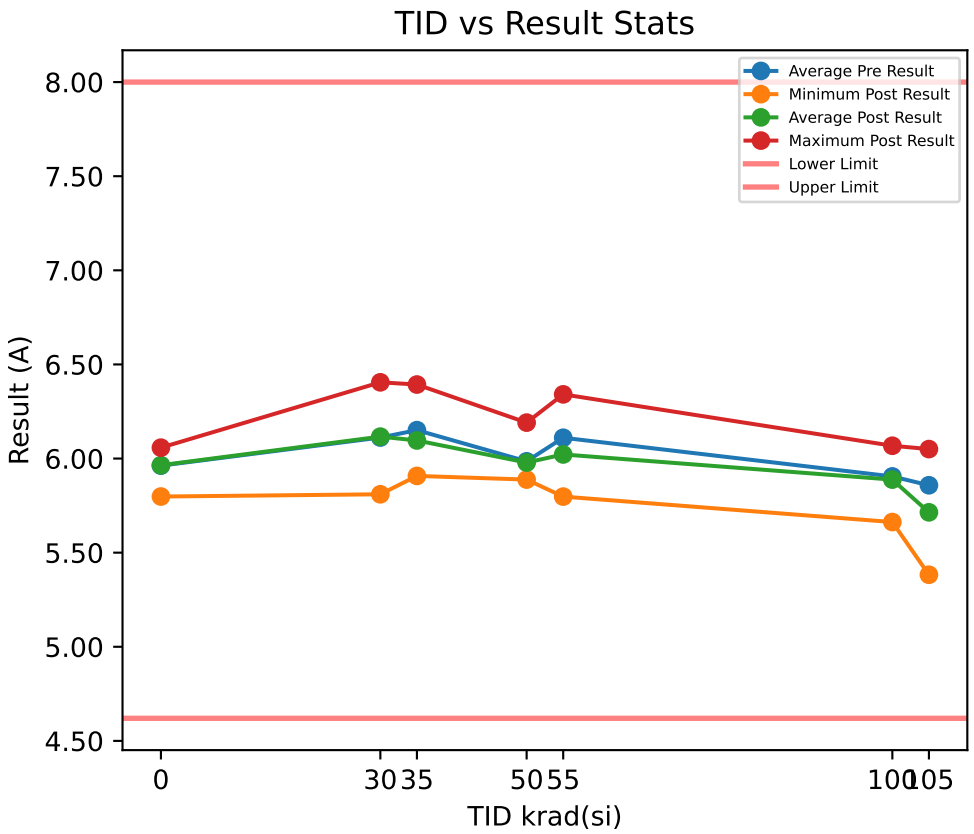
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

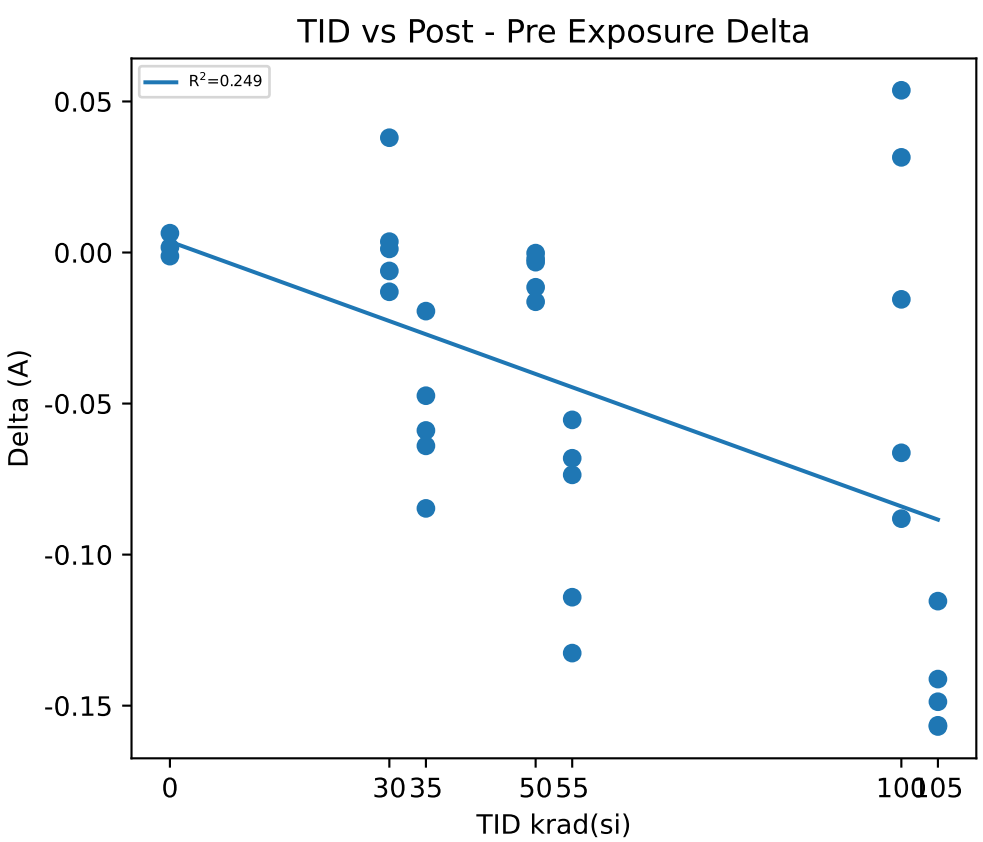
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0463	6.0428	-0.0035
2	0	CU2	6.2041	6.2031	-0.001
3	0	CU3	6.1465	6.1435	-0.003
11	30	Unbiased-30krad	6.1094	6.1158	0.0064
12	30	Unbiased-30krad	6.2644	6.2857	0.0213
13	30	Unbiased-30krad	6.3418	6.341	-0.0008
14	30	Unbiased-30krad	6.0463	6.0258	-0.0205
15	30	Unbiased-30krad	5.8924	5.9077	0.0153
16	35	Biased-30krad	6.3891	6.3256	-0.0635
17	35	Biased-30krad	6.0411	5.9803	-0.0608
18	35	Biased-30krad	6.1745	6.1202	-0.0543
19	35	Biased-30krad	6.3272	6.2695	-0.0577
20	35	Biased-30krad	5.9393	5.8891	-0.0502
30	50	Unbiased-50krad	5.8683	5.9152	0.0469
31	50	Unbiased-50krad	5.961	5.9732	0.0122
32	50	Unbiased-50krad	5.8774	5.831	-0.0464
33	50	Unbiased-50krad	6.1844	6.1632	-0.0212
34	50	Unbiased-50krad	5.9666	5.9906	0.024
40	55	Biased-50krad	6.1772	6.0554	-0.1218
41	55	Biased-50krad	6.092	5.9756	-0.1164
42	55	Biased-50krad	6.0612	5.9835	-0.0777
43	55	Biased-50krad	5.6876	5.6074	-0.0802
44	55	Biased-50krad	6.18	6.1285	-0.0515
45	100	Unbiased-100krad	6.1086	6.1356	0.027
46	100	Unbiased-100krad	6.019	6.0206	0.0016
47	100	Unbiased-100krad	5.7689	5.7603	-0.0086
48	100	Unbiased-100krad	6.0968	6.0811	-0.0157
49	100	Unbiased-100krad	5.8636	5.8555	-0.0081
50	105	Biased-100krad	6.1847	6.0127	-0.172
51	105	Biased-100krad	5.7369	5.6375	-0.0994
52	105	Biased-100krad	5.7618	5.5624	-0.1994
53	105	Biased-100krad	5.7539	5.643	-0.1109
54	105	Biased-100krad	5.892	5.7504	-0.1416

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0463	6.1323	6.2041	0.079853	6.0428	6.1298	6.2031	0.081023	-0.0035	-0.0025	-0.001	0.0013229
30	5.8924	6.1309	6.3418	0.17805	5.9077	6.1352	6.341	0.17966	-0.0205	0.00434	0.0213	0.016244
35	5.9393	6.1742	6.3891	0.18874	5.8891	6.1169	6.3256	0.18534	-0.0635	-0.0573	-0.0502	0.0052502
50	5.8683	5.9715	6.1844	0.12744	5.831	5.9746	6.1632	0.12245	-0.0464	0.0031	0.0469	0.037009
55	5.6876	6.0396	6.18	0.20357	5.6074	5.9501	6.1285	0.20132	-0.1218	-0.08952	-0.0515	0.029311
100	5.7689	5.9714	6.1086	0.14953	5.7603	5.9706	6.1356	0.15765	-0.0157	-0.00076	0.027	0.016694
105	5.7369	5.8659	6.1847	0.18864	5.5624	5.7212	6.0127	0.17618	-0.1994	-0.14466	-0.0994	0.041658

Device Test: 77.3 _ILIM_LS|LS_Sourcing/SW2/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





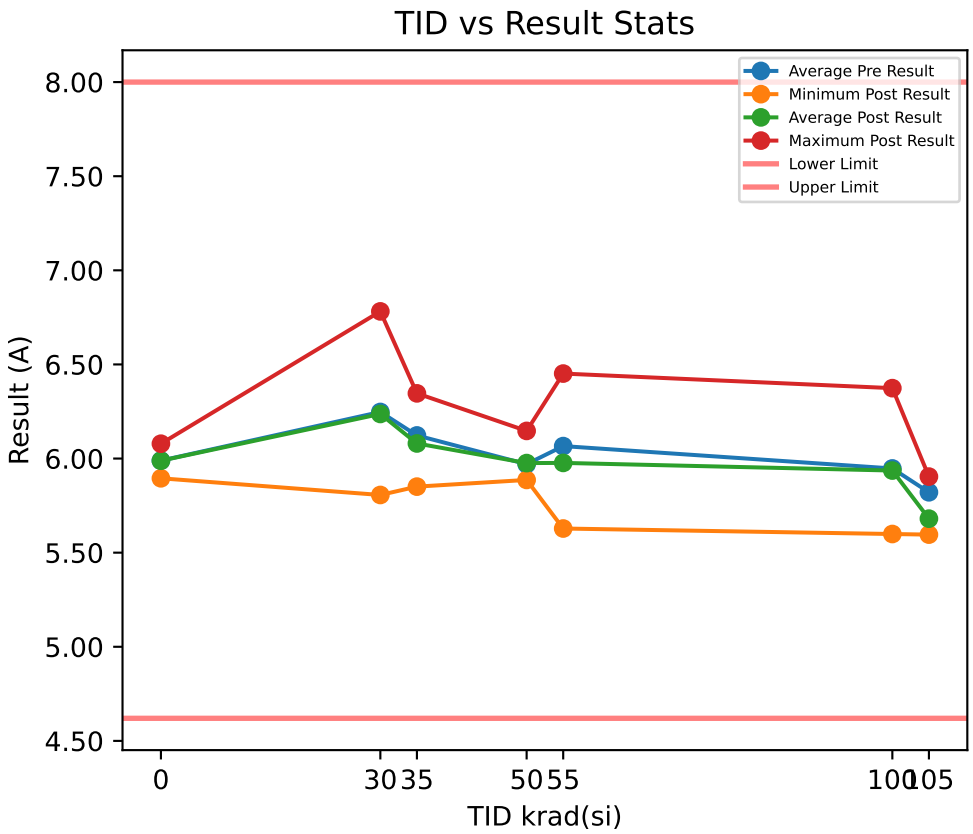
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

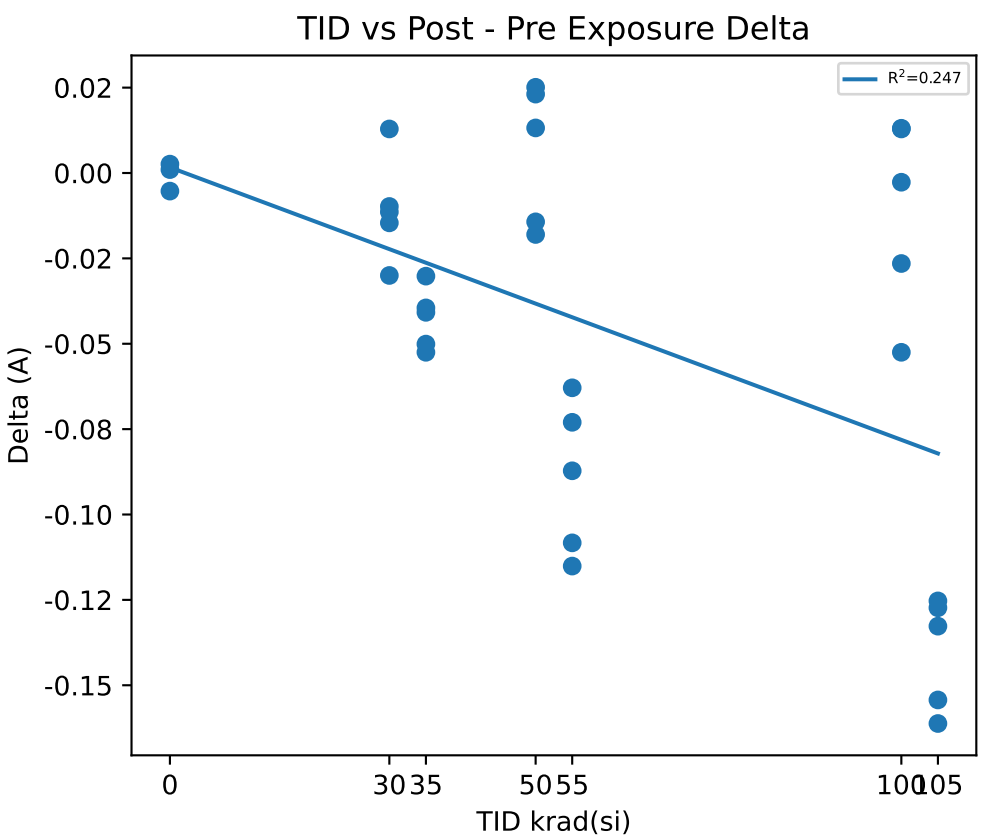
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0561	6.0578	0.0017
2	0	CU2	5.7918	5.7982	0.0064
3	0	CU3	6.0392	6.038	-0.0012
11	30	Unbiased-30krad	6.2944	6.298	0.0036
12	30	Unbiased-30krad	5.8162	5.8101	-0.0061
13	30	Unbiased-30krad	6.367	6.405	0.038
14	30	Unbiased-30krad	6.0964	6.0834	-0.013
15	30	Unbiased-30krad	5.9843	5.9855	0.0012
16	35	Biased-30krad	6.3165	6.2691	-0.0474
17	35	Biased-30krad	5.9666	5.9077	-0.0589
18	35	Biased-30krad	5.9871	5.9677	-0.0194
19	35	Biased-30krad	6.0064	5.9424	-0.064
20	35	Biased-30krad	6.4779	6.3932	-0.0847
30	50	Unbiased-50krad	5.9366	5.9203	-0.0163
31	50	Unbiased-50krad	5.9914	5.9882	-0.0032
32	50	Unbiased-50krad	5.9168	5.9053	-0.0115
33	50	Unbiased-50krad	6.1911	6.1909	-0.0002
34	50	Unbiased-50krad	5.8904	5.8883	-0.0021
40	55	Biased-50krad	5.9117	5.8381	-0.0736
41	55	Biased-50krad	6.367	6.2529	-0.1141
42	55	Biased-50krad	6.4736	6.341	-0.1326
43	55	Biased-50krad	5.9342	5.8788	-0.0554
44	55	Biased-50krad	5.8659	5.7978	-0.0681
45	100	Unbiased-100krad	5.8943	5.8788	-0.0155
46	100	Unbiased-100krad	5.946	5.8579	-0.0881
47	100	Unbiased-100krad	5.729	5.6627	-0.0663
48	100	Unbiased-100krad	6.0143	6.068	0.0537
49	100	Unbiased-100krad	5.9417	5.9732	0.0315
50	105	Biased-100krad	6.1915	6.0503	-0.1412
51	105	Biased-100krad	5.5988	5.4834	-0.1154
52	105	Biased-100krad	5.5314	5.3827	-0.1487
53	105	Biased-100krad	5.9666	5.8097	-0.1569
54	105	Biased-100krad	6.0017	5.8452	-0.1565

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7918	5.9624	6.0561	0.14796	5.7982	5.9647	6.0578	0.1445	-0.0012	0.0023	0.0064	0.0038354
30	5.8162	6.1117	6.367	0.22491	5.8101	6.1164	6.405	0.23891	-0.013	0.00474	0.038	0.019699
35	5.9666	6.1509	6.4779	0.23239	5.9077	6.096	6.3932	0.22011	-0.0847	-0.05488	-0.0194	0.023997
50	5.8904	5.9853	6.1911	0.12089	5.8883	5.9786	6.1909	0.12459	-0.0163	-0.00666	-0.0002	0.0069075
55	5.8659	6.1105	6.4736	0.28639	5.7978	6.0217	6.341	0.25479	-0.1326	-0.08876	-0.0554	0.032915
100	5.729	5.9051	6.0143	0.10731	5.6627	5.8881	6.068	0.15117	-0.0881	-0.01694	0.0537	0.060907
105	5.5314	5.858	6.1915	0.28174	5.3827	5.7143	6.0503	0.27496	-0.1569	-0.14374	-0.1154	0.017104

Device Test: 77.4 _ILIM_LS|LS_Sourcing/SW3/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





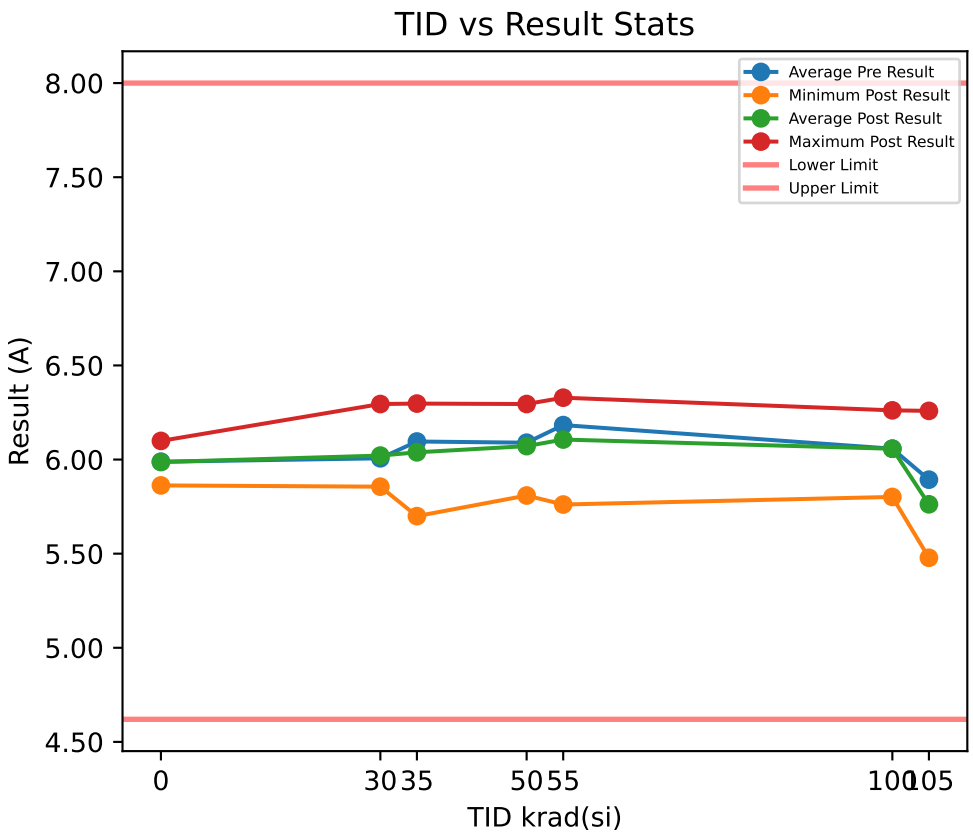
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

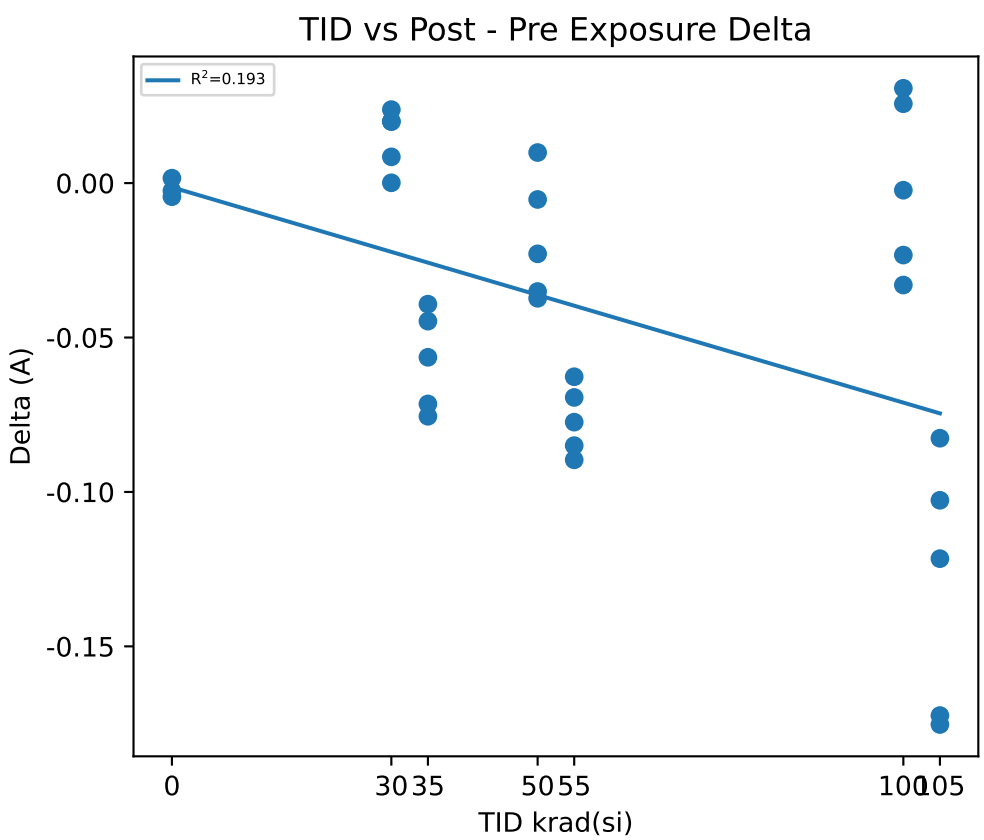
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8941	5.8951	0.001
2	0	CU2	5.9889	5.9915	0.0026
3	0	CU3	6.0841	6.0788	-0.0053
11	30	Unbiased-30krad	6.336	6.3262	-0.0098
12	30	Unbiased-30krad	6.7964	6.7818	-0.0146
13	30	Unbiased-30krad	6.2689	6.2389	-0.03
14	30	Unbiased-30krad	6.0181	6.031	0.0129
15	30	Unbiased-30krad	5.8179	5.8065	-0.0114
16	35	Biased-30krad	6.0165	5.9757	-0.0408
17	35	Biased-30krad	6.0766	6.0464	-0.0302
18	35	Biased-30krad	6.2211	6.1816	-0.0395
19	35	Biased-30krad	6.3988	6.3463	-0.0525
20	35	Biased-30krad	5.9009	5.8508	-0.0501
30	50	Unbiased-50krad	5.9186	5.9437	0.0251
31	50	Unbiased-50krad	5.8633	5.8864	0.0231
32	50	Unbiased-50krad	5.8787	5.8919	0.0132
33	50	Unbiased-50krad	6.0288	6.0108	-0.018
34	50	Unbiased-50krad	6.1611	6.1468	-0.0143
40	55	Biased-50krad	6.2239	6.1156	-0.1083
41	55	Biased-50krad	5.9431	5.8559	-0.0872
42	55	Biased-50krad	6.5666	6.4515	-0.1151
43	55	Biased-50krad	5.6912	5.6283	-0.0629
44	55	Biased-50krad	5.906	5.833	-0.073
45	100	Unbiased-100krad	5.6533	5.6662	0.0129
46	100	Unbiased-100krad	5.6256	5.5991	-0.0265
47	100	Unbiased-100krad	5.8258	5.8231	-0.0027
48	100	Unbiased-100krad	6.3609	6.374	0.0131
49	100	Unbiased-100krad	6.2712	6.2187	-0.0525
50	105	Biased-100krad	5.8009	5.6682	-0.1327
51	105	Biased-100krad	5.7232	5.5959	-0.1273
52	105	Biased-100krad	5.7512	5.6259	-0.1253
53	105	Biased-100krad	5.7701	5.6089	-0.1612
54	105	Biased-100krad	6.0584	5.9041	-0.1543

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8941	5.989	6.0841	0.095	5.8951	5.9885	6.0788	0.091888	-0.0053	-0.00056667	0.0026	0.0041765
30	5.8179	6.2475	6.7964	0.36972	5.8065	6.2369	6.7818	0.36487	-0.03	-0.01058	0.0129	0.015378
35	5.9009	6.1228	6.3988	0.19269	5.8508	6.0802	6.3463	0.1909	-0.0525	-0.04262	-0.0302	0.0089564
50	5.8633	5.9701	6.1611	0.12484	5.8864	5.9759	6.1468	0.10785	-0.018	0.00582	0.0251	0.020597
55	5.6912	6.0662	6.5666	0.3379	5.6283	5.9769	6.4515	0.31676	-0.1151	-0.0893	-0.0629	0.022325
100	5.6256	5.9474	6.3609	0.34665	5.5991	5.9362	6.374	0.34308	-0.0525	-0.01114	0.0131	0.02821
105	5.7232	5.8208	6.0584	0.13582	5.5959	5.6806	5.9041	0.12788	-0.1612	-0.14016	-0.1253	0.016466

Device Test: 77.5 _ILIM_LS|LS_Sourcing/SW4/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





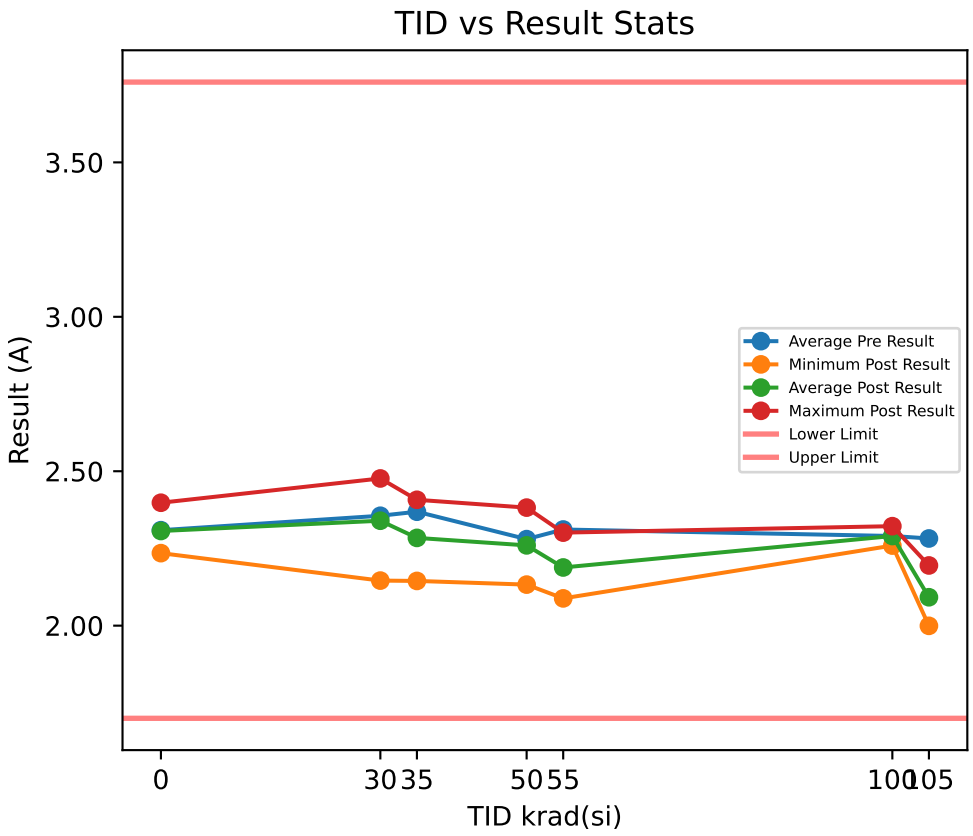
Test Results (Lower Limit = 4.62, Upper Limit = 8.0 (A))

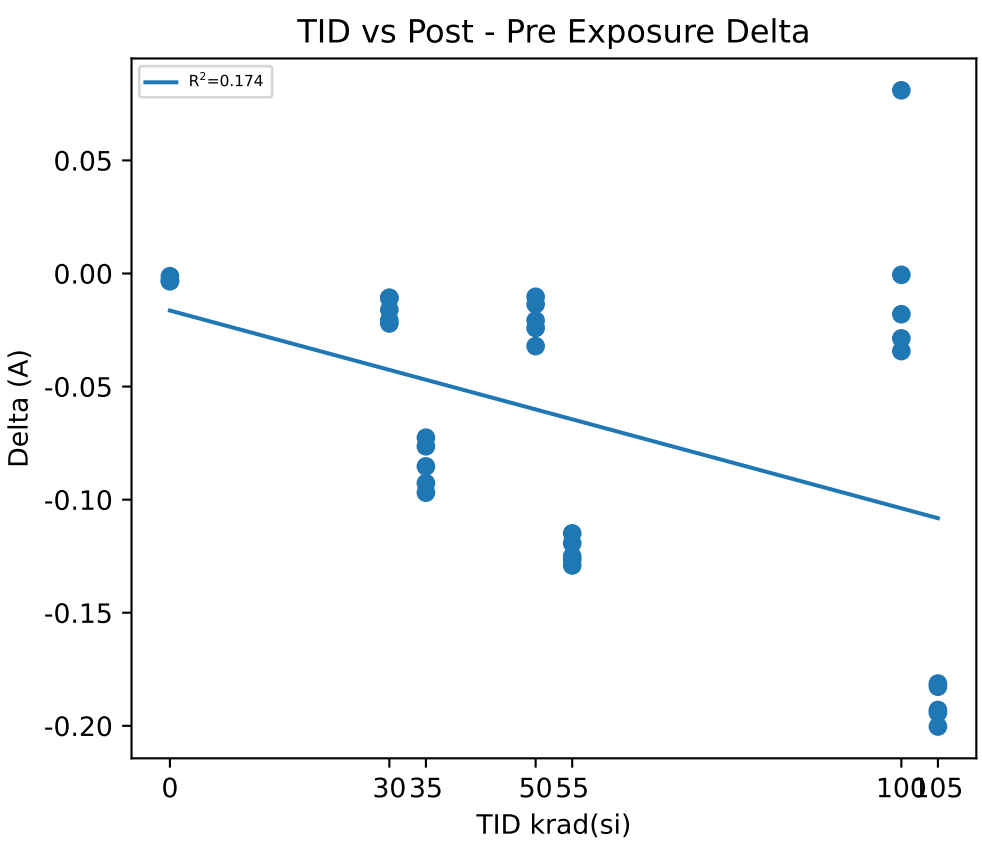
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0011	5.9986	-0.0025
2	0	CU2	5.861	5.8626	0.0016
3	0	CU3	6.1034	6.099	-0.0044
11	30	Unbiased-30krad	5.9431	5.9516	0.0085
12	30	Unbiased-30krad	5.979	5.999	0.02
13	30	Unbiased-30krad	6.2712	6.295	0.0238
14	30	Unbiased-30krad	5.8558	5.8559	0.0001
15	30	Unbiased-30krad	5.9838	6.0037	0.0199
16	35	Biased-30krad	6.3688	6.2973	-0.0715
17	35	Biased-30krad	6.259	6.1835	-0.0755
18	35	Biased-30krad	6.216	6.1713	-0.0447
19	35	Biased-30krad	5.8969	5.8405	-0.0564
20	35	Biased-30krad	5.7386	5.6994	-0.0392
30	50	Unbiased-50krad	6.2851	6.295	0.0099
31	50	Unbiased-50krad	6.2013	6.1784	-0.0229
32	50	Unbiased-50krad	6.0687	6.0634	-0.0053
33	50	Unbiased-50krad	6.0485	6.0112	-0.0373
34	50	Unbiased-50krad	5.844	5.8089	-0.0351
40	55	Biased-50krad	6.3088	6.2238	-0.085
41	55	Biased-50krad	6.3913	6.3139	-0.0774
42	55	Biased-50krad	6.3913	6.3286	-0.0627
43	55	Biased-50krad	5.9735	5.9041	-0.0694
44	55	Biased-50krad	5.8507	5.7611	-0.0896
45	100	Unbiased-100krad	6.2847	6.2614	-0.0233
46	100	Unbiased-100krad	5.9087	5.8757	-0.033
47	100	Unbiased-100krad	5.7757	5.8014	0.0257
48	100	Unbiased-100krad	6.2558	6.2535	-0.0023
49	100	Unbiased-100krad	6.0639	6.0946	0.0307
50	105	Biased-100krad	6.3613	6.2586	-0.1027
51	105	Biased-100krad	5.6556	5.573	-0.0826
52	105	Biased-100krad	5.8847	5.7631	-0.1216
53	105	Biased-100krad	5.6505	5.4781	-0.1724
54	105	Biased-100krad	5.9135	5.7382	-0.1753

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.861	5.9885	6.1034	0.12169	5.8626	5.9867	6.099	0.11865	-0.0044	-0.0017667	0.0016	0.0030665
30	5.8558	6.0066	6.2712	0.15658	5.8559	6.021	6.295	0.16427	0.0001	0.01446	0.0238	0.0098647
35	5.7386	6.0959	6.3688	0.26588	5.6994	6.0384	6.2973	0.25487	-0.0755	-0.05746	-0.0392	0.015968
50	5.844	6.0895	6.2851	0.16818	5.8089	6.0714	6.295	0.18306	-0.0373	-0.01814	0.0099	0.020177
55	5.8507	6.1831	6.3913	0.25343	5.7611	6.1063	6.3286	0.25805	-0.0896	-0.07682	-0.0627	0.011011
100	5.7757	6.0578	6.2847	0.21939	5.8014	6.0573	6.2614	0.21214	-0.033	-0.00044	0.0307	0.028457
105	5.6505	5.8931	6.3613	0.28938	5.4781	5.7622	6.2586	0.30145	-0.1753	-0.13092	-0.0826	0.041558

Device Test: 77.6 _ILIM_LS|LS_Sinking/SW1/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK





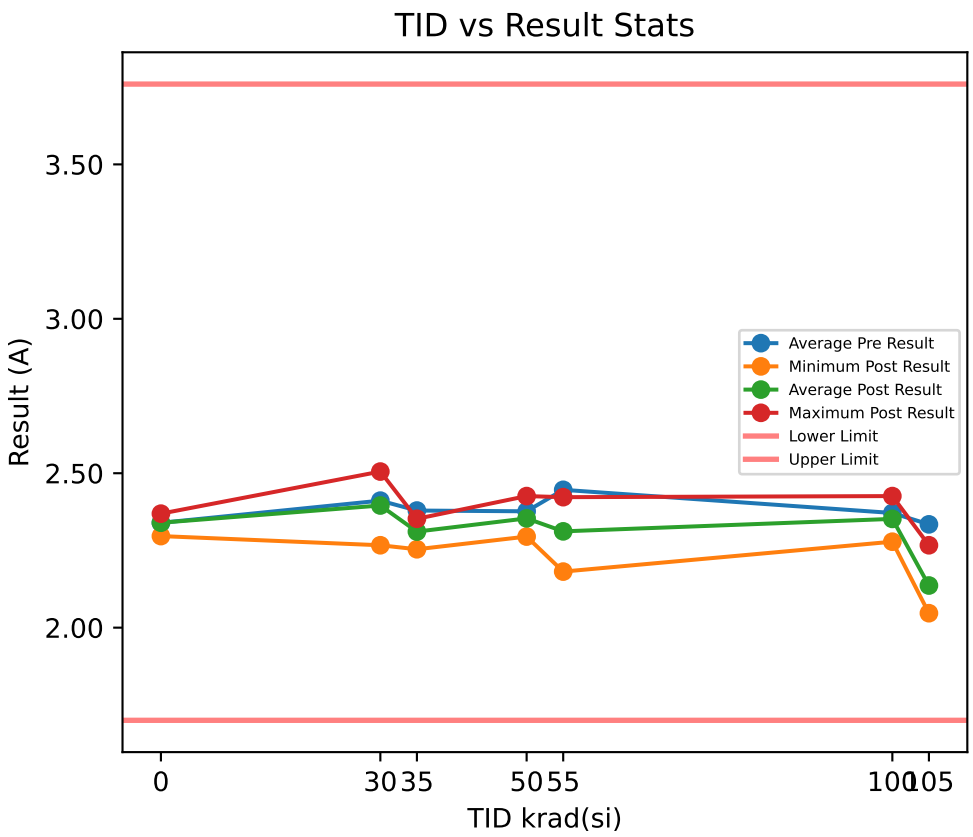
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

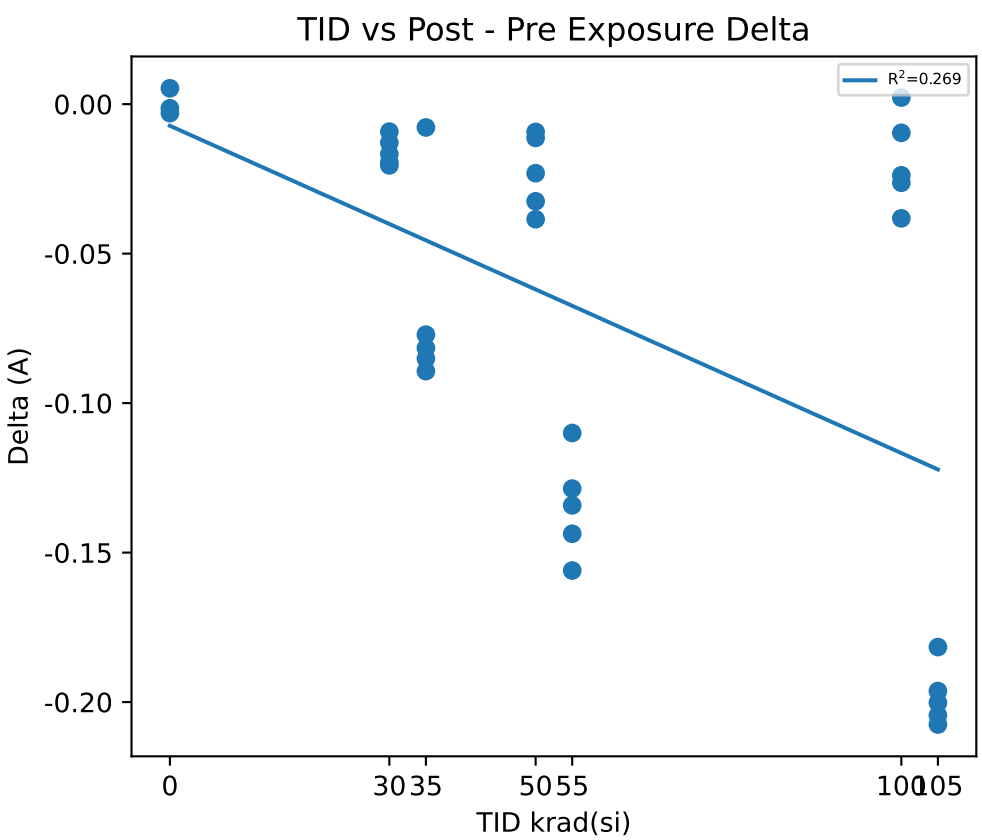
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.29	2.2866	-0.0034
2	0	CU2	2.4013	2.398	-0.0033
3	0	CU3	2.236	2.2348	-0.0012
11	30	Unbiased-30krad	2.3539	2.3332	-0.0207
12	30	Unbiased-30krad	2.4987	2.4766	-0.0221
13	30	Unbiased-30krad	2.451	2.4402	-0.0108
14	30	Unbiased-30krad	2.3188	2.3028	-0.016
15	30	Unbiased-30krad	2.1567	2.1459	-0.0108
16	35	Biased-30krad	2.451	2.3541	-0.0969
17	35	Biased-30krad	2.2387	2.1661	-0.0726
18	35	Biased-30krad	2.4246	2.3482	-0.0764
19	35	Biased-30krad	2.4928	2.4075	-0.0853
20	35	Biased-30krad	2.2375	2.1448	-0.0927
30	50	Unbiased-50krad	2.3243	2.3107	-0.0136
31	50	Unbiased-50krad	2.2537	2.2329	-0.0208
32	50	Unbiased-50krad	2.1432	2.1329	-0.0103
33	50	Unbiased-50krad	2.4143	2.3822	-0.0321
34	50	Unbiased-50krad	2.2652	2.2411	-0.0241
40	55	Biased-50krad	2.4277	2.3012	-0.1265
41	55	Biased-50krad	2.3066	2.1775	-0.1291
42	55	Biased-50krad	2.3614	2.2364	-0.125
43	55	Biased-50krad	2.2032	2.0883	-0.1149
44	55	Biased-50krad	2.2577	2.1384	-0.1193
45	100	Unbiased-100krad	2.3401	2.3221	-0.018
46	100	Unbiased-100krad	2.2971	2.2965	-0.0006
47	100	Unbiased-100krad	2.2936	2.2593	-0.0343
48	100	Unbiased-100krad	2.3299	2.3012	-0.0287
49	100	Unbiased-100krad	2.191	2.272	0.081
50	105	Biased-100krad	2.3776	2.1949	-0.1827
51	105	Biased-100krad	2.1807	1.9994	-0.1813
52	105	Biased-100krad	2.2293	2.029	-0.2003
53	105	Biased-100krad	2.3093	2.1151	-0.1942
54	105	Biased-100krad	2.3145	2.1215	-0.193

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.236	2.3091	2.4013	0.084289	2.2348	2.3065	2.398	0.083394	-0.0034	-0.0026333	-0.0012	0.0012423
30	2.1567	2.3558	2.4987	0.13276	2.1459	2.3397	2.4766	0.1302	-0.0221	-0.01608	-0.0108	0.0053233
35	2.2375	2.3689	2.4928	0.12187	2.1448	2.2841	2.4075	0.11996	-0.0969	-0.08478	-0.0726	0.01035
50	2.1432	2.2801	2.4143	0.099529	2.1329	2.26	2.3822	0.093206	-0.0321	-0.02018	-0.0103	0.0086422
55	2.2032	2.3113	2.4277	0.087521	2.0883	2.1884	2.3012	0.083166	-0.1291	-0.12296	-0.1149	0.0057609
100	2.191	2.2903	2.3401	0.059089	2.2593	2.2902	2.3221	0.024821	-0.0343	-0.00012	0.081	0.047131
105	2.1807	2.2823	2.3776	0.077427	1.9994	2.092	2.1949	0.07832	-0.2003	-0.1903	-0.1813	0.0080818

Device Test: 77.7 _ILIM_LS|LS_Sinking/SW2/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK





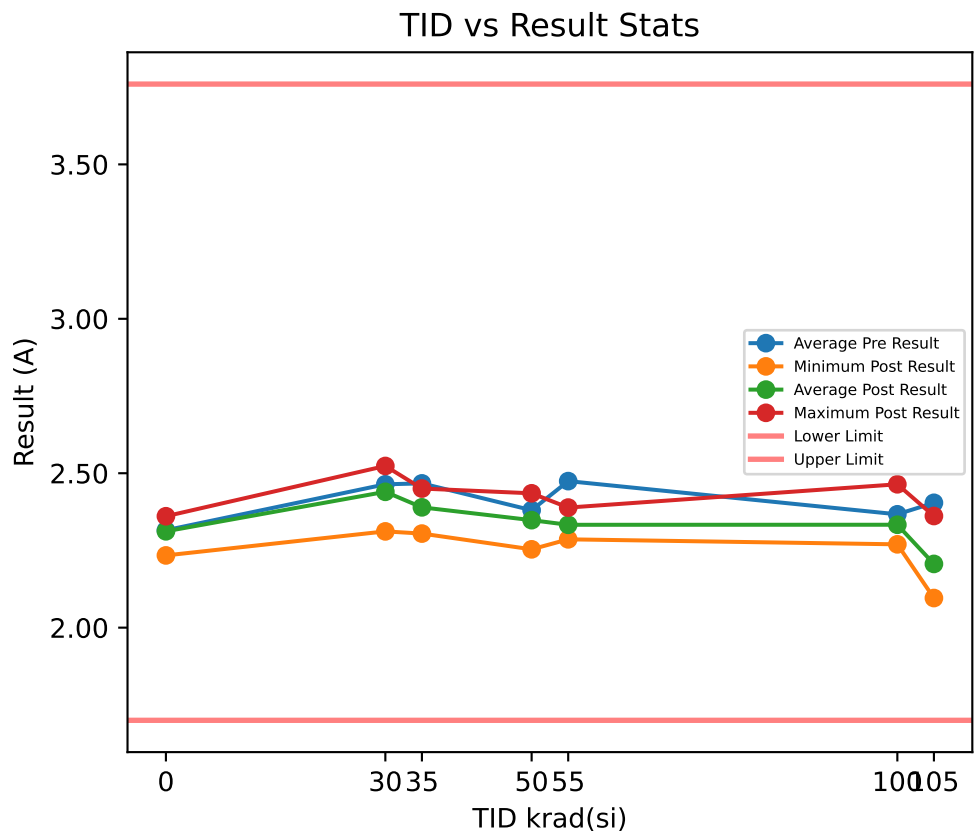
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

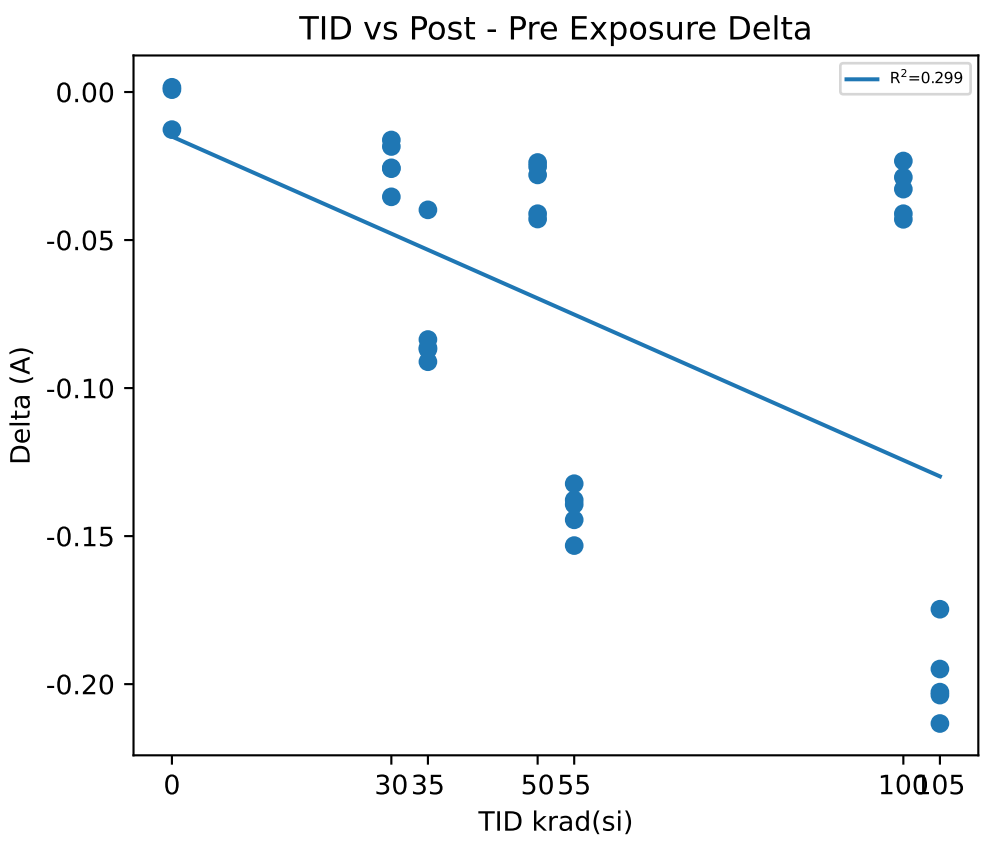
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3551	2.3537	-0.0014
2	0	CU2	2.2912	2.2965	0.0053
3	0	CU3	2.3721	2.3691	-0.003
11	30	Unbiased-30krad	2.4976	2.4809	-0.0167
12	30	Unbiased-30krad	2.2936	2.2807	-0.0129
13	30	Unbiased-30krad	2.5248	2.5054	-0.0194
14	30	Unbiased-30krad	2.453	2.4438	-0.0092
15	30	Unbiased-30krad	2.2873	2.2668	-0.0205
16	35	Biased-30krad	2.3973	2.3202	-0.0771
17	35	Biased-30krad	2.3741	2.2925	-0.0816
18	35	Biased-30krad	2.2616	2.2538	-0.0078
19	35	Biased-30krad	2.4376	2.3525	-0.0851
20	35	Biased-30krad	2.4253	2.336	-0.0893
30	50	Unbiased-50krad	2.3042	2.2949	-0.0093
31	50	Unbiased-50krad	2.3322	2.3209	-0.0113
32	50	Unbiased-50krad	2.395	2.3565	-0.0385
33	50	Unbiased-50krad	2.4585	2.426	-0.0325
34	50	Unbiased-50krad	2.3938	2.3707	-0.0231
40	55	Biased-50krad	2.3938	2.2838	-0.11
41	55	Biased-50krad	2.5662	2.4225	-0.1437
42	55	Biased-50krad	2.5769	2.4209	-0.156
43	55	Biased-50krad	2.3788	2.2502	-0.1286
44	55	Biased-50krad	2.3157	2.1815	-0.1342
45	100	Unbiased-100krad	2.3788	2.381	0.0022
46	100	Unbiased-100krad	2.3137	2.2874	-0.0263
47	100	Unbiased-100krad	2.3165	2.2783	-0.0382
48	100	Unbiased-100krad	2.4498	2.426	-0.0238
49	100	Unbiased-100krad	2.3977	2.3881	-0.0096
50	105	Biased-100krad	2.4743	2.2668	-0.2075
51	105	Biased-100krad	2.2675	2.0859	-0.1816
52	105	Biased-100krad	2.2431	2.0468	-0.1963
53	105	Biased-100krad	2.2703	2.0701	-0.2002
54	105	Biased-100krad	2.4171	2.2127	-0.2044

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2912	2.3395	2.3721	0.042656	2.2965	2.3398	2.3691	0.038253	-0.003	0.0003	0.0053	0.0044034
30	2.2873	2.4113	2.5248	0.11325	2.2668	2.3955	2.5054	0.11341	-0.0205	-0.01574	-0.0092	0.0046854
35	2.2616	2.3792	2.4376	0.070212	2.2538	2.311	2.3525	0.038878	-0.0893	-0.06818	-0.0078	0.034051
50	2.3042	2.3767	2.4585	0.060322	2.2949	2.3538	2.426	0.050143	-0.0385	-0.02294	-0.0093	0.012797
55	2.3157	2.4463	2.5769	0.11811	2.1815	2.3118	2.4225	0.1069	-0.156	-0.1345	-0.11	0.01719
100	2.3137	2.3713	2.4498	0.057524	2.2783	2.3522	2.426	0.065622	-0.0382	-0.01914	0.0022	0.015674
105	2.2431	2.3345	2.4743	0.10408	2.0468	2.1365	2.2668	0.097211	-0.2075	-0.198	-0.1816	0.010098

Device Test: 77.8 _ILIM_LS|LS_Sinking/SW3/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK





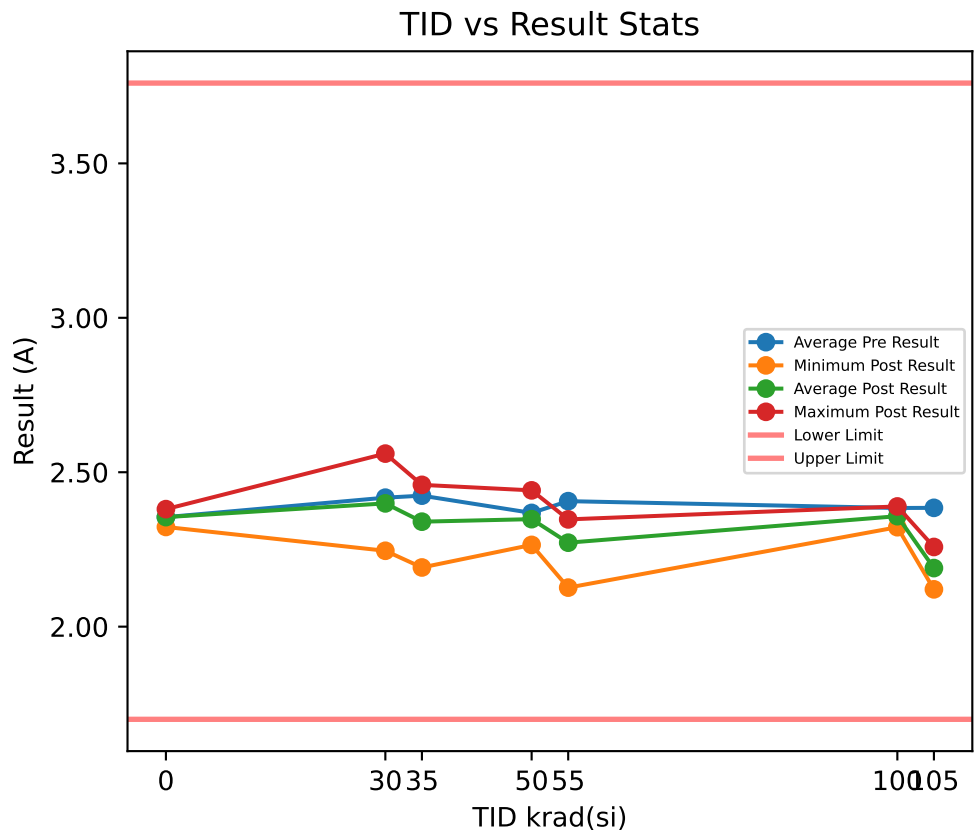
Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

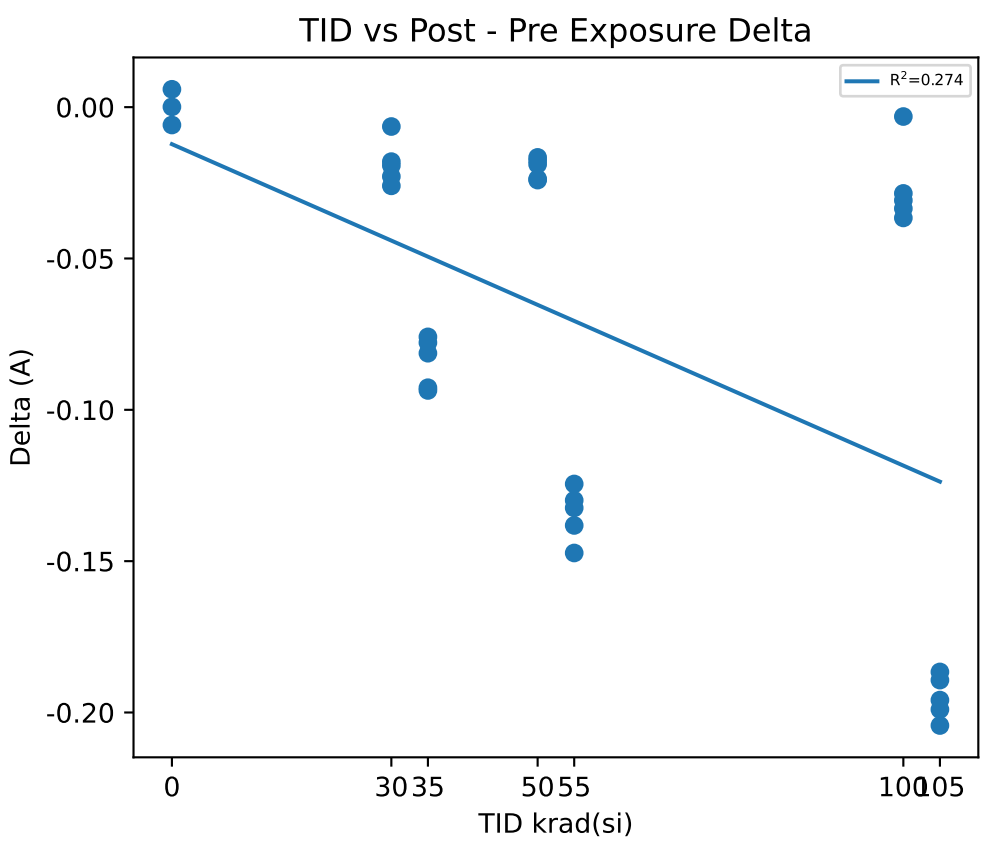
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3591	2.3607	0.0016
2	0	CU2	2.3405	2.3413	0.0008
3	0	CU3	2.2466	2.2339	-0.0127
11	30	Unbiased-30krad	2.4866	2.4512	-0.0354
12	30	Unbiased-30krad	2.4393	2.4137	-0.0256
13	30	Unbiased-30krad	2.5419	2.5235	-0.0184
14	30	Unbiased-30krad	2.5249	2.499	-0.0259
15	30	Unbiased-30krad	2.3279	2.3117	-0.0162
16	35	Biased-30krad	2.5261	2.435	-0.0911
17	35	Biased-30krad	2.4633	2.3769	-0.0864
18	35	Biased-30krad	2.4902	2.4504	-0.0398
19	35	Biased-30krad	2.4645	2.3809	-0.0836
20	35	Biased-30krad	2.3915	2.3046	-0.0869
30	50	Unbiased-50krad	2.3168	2.2888	-0.028
31	50	Unbiased-50krad	2.2774	2.2536	-0.0238
32	50	Unbiased-50krad	2.3832	2.3421	-0.0411
33	50	Unbiased-50krad	2.4637	2.4208	-0.0429
34	50	Unbiased-50krad	2.4602	2.435	-0.0252
40	55	Biased-50krad	2.4831	2.3386	-0.1445
41	55	Biased-50krad	2.4633	2.3255	-0.1378
42	55	Biased-50krad	2.5281	2.3888	-0.1393
43	55	Biased-50krad	2.4183	2.286	-0.1323
44	55	Biased-50krad	2.4795	2.3263	-0.1532
45	100	Unbiased-100krad	2.3109	2.2698	-0.0411
46	100	Unbiased-100krad	2.2983	2.275	-0.0233
47	100	Unbiased-100krad	2.3536	2.3208	-0.0328
48	100	Unbiased-100krad	2.493	2.4642	-0.0288
49	100	Unbiased-100krad	2.3792	2.3362	-0.043
50	105	Biased-100krad	2.5652	2.3615	-0.2037
51	105	Biased-100krad	2.3303	2.1556	-0.1747
52	105	Biased-100krad	2.2908	2.0959	-0.1949
53	105	Biased-100krad	2.38	2.1773	-0.2027
54	105	Biased-100krad	2.4547	2.2414	-0.2133

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2466	2.3154	2.3591	0.060304	2.2339	2.312	2.3607	0.0683	-0.0127	-0.0034333	0.0016	0.0080351
30	2.3279	2.4641	2.5419	0.085763	2.3117	2.4398	2.5235	0.083263	-0.0354	-0.0243	-0.0162	0.0075478
35	2.3915	2.4671	2.5261	0.049374	2.3046	2.3896	2.4504	0.057489	-0.0911	-0.07756	-0.0398	0.021278
50	2.2774	2.3803	2.4637	0.083619	2.2536	2.3481	2.435	0.079561	-0.0429	-0.0322	-0.0238	0.0090953
55	2.4183	2.4745	2.5281	0.039547	2.286	2.333	2.3888	0.036929	-0.1532	-0.14142	-0.1323	0.0078903
100	2.2983	2.367	2.493	0.077575	2.2698	2.3332	2.4642	0.07863	-0.043	-0.0338	-0.0233	0.0082792
105	2.2908	2.4042	2.5652	0.10883	2.0959	2.2063	2.3615	0.10114	-0.2133	-0.19786	-0.1747	0.014501

Device Test: 77.9 _ILIM_LS|LS_Sinking/SW4/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK





Test Results (Lower Limit = 1.7, Upper Limit = 3.76 (A))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3287	2.3228	-0.0059
2	0	CU2	2.3548	2.3607	0.0059
3	0	CU3	2.3804	2.3805	0.0001
11	30	Unbiased-30krad	2.4389	2.416	-0.0229
12	30	Unbiased-30krad	2.5783	2.5603	-0.018
13	30	Unbiased-30krad	2.412	2.386	-0.026
14	30	Unbiased-30krad	2.4069	2.3876	-0.0193
15	30	Unbiased-30krad	2.2521	2.2457	-0.0064
16	35	Biased-30krad	2.4566	2.3753	-0.0813
17	35	Biased-30krad	2.3986	2.305	-0.0936
18	35	Biased-30krad	2.5518	2.4591	-0.0927
19	35	Biased-30krad	2.4464	2.3686	-0.0778
20	35	Biased-30krad	2.2675	2.1916	-0.0759
30	50	Unbiased-50krad	2.4602	2.4413	-0.0189
31	50	Unbiased-50krad	2.4231	2.4065	-0.0166
32	50	Unbiased-50krad	2.3666	2.3489	-0.0177
33	50	Unbiased-50krad	2.303	2.2789	-0.0241
34	50	Unbiased-50krad	2.2884	2.2647	-0.0237
40	55	Biased-50krad	2.4855	2.3473	-0.1382
41	55	Biased-50krad	2.4456	2.3157	-0.1299
42	55	Biased-50krad	2.4803	2.333	-0.1473
43	55	Biased-50krad	2.2509	2.1264	-0.1245
44	55	Biased-50krad	2.3694	2.237	-0.1324
45	100	Unbiased-100krad	2.395	2.3615	-0.0335
46	100	Unbiased-100krad	2.4049	2.3741	-0.0308
47	100	Unbiased-100krad	2.3702	2.3417	-0.0285
48	100	Unbiased-100krad	2.4258	2.3892	-0.0366
49	100	Unbiased-100krad	2.3251	2.322	-0.0031
50	105	Biased-100krad	2.457	2.258	-0.199
51	105	Biased-100krad	2.3251	2.1358	-0.1893
52	105	Biased-100krad	2.4337	2.2378	-0.1959
53	105	Biased-100krad	2.3074	2.1208	-0.1866
54	105	Biased-100krad	2.4002	2.1959	-0.2043

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3287	2.3546	2.3804	0.02585	2.3228	2.3547	2.3805	0.029319	-0.0059	3.3333e-05	0.0059	0.0059003
30	2.2521	2.4176	2.5783	0.11599	2.2457	2.3991	2.5603	0.11192	-0.026	-0.01852	-0.0064	0.0074651
35	2.2675	2.4242	2.5518	0.10372	2.1916	2.3399	2.4591	0.099368	-0.0936	-0.08426	-0.0759	0.0083494
50	2.2884	2.3683	2.4602	0.07433	2.2647	2.3481	2.4413	0.077204	-0.0241	-0.0202	-0.0166	0.0034771
55	2.2509	2.4063	2.4855	0.098494	2.1264	2.2719	2.3473	0.091822	-0.1473	-0.13446	-0.1245	0.0087048
100	2.3251	2.3842	2.4258	0.038615	2.322	2.3577	2.3892	0.026487	-0.0366	-0.0265	-0.0031	0.013426
105	2.3074	2.3847	2.457	0.065947	2.1208	2.1897	2.258	0.060559	-0.2043	-0.19502	-0.1866	0.0071824

B Appendix: LDR TID Report Data

This appendix contains the LDR TID report data.

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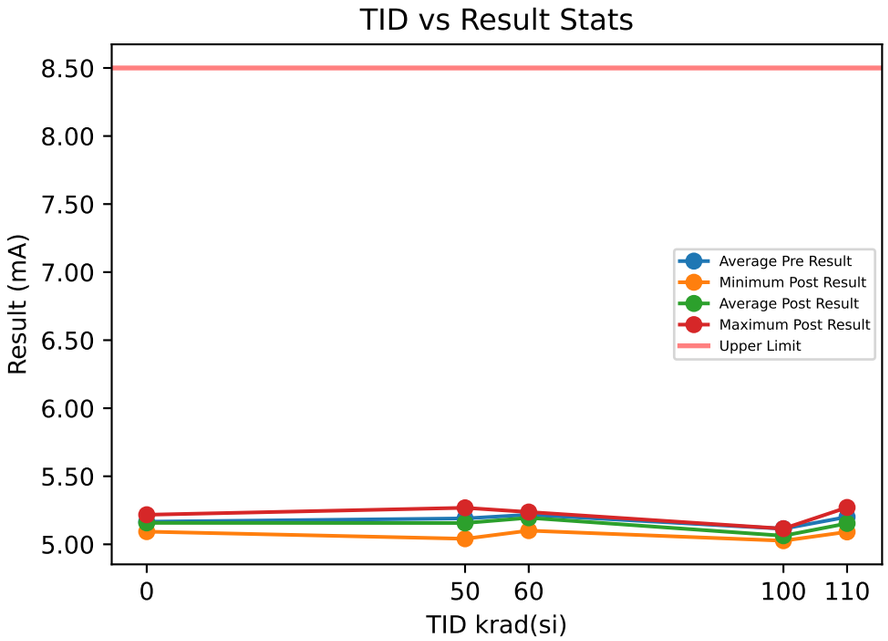
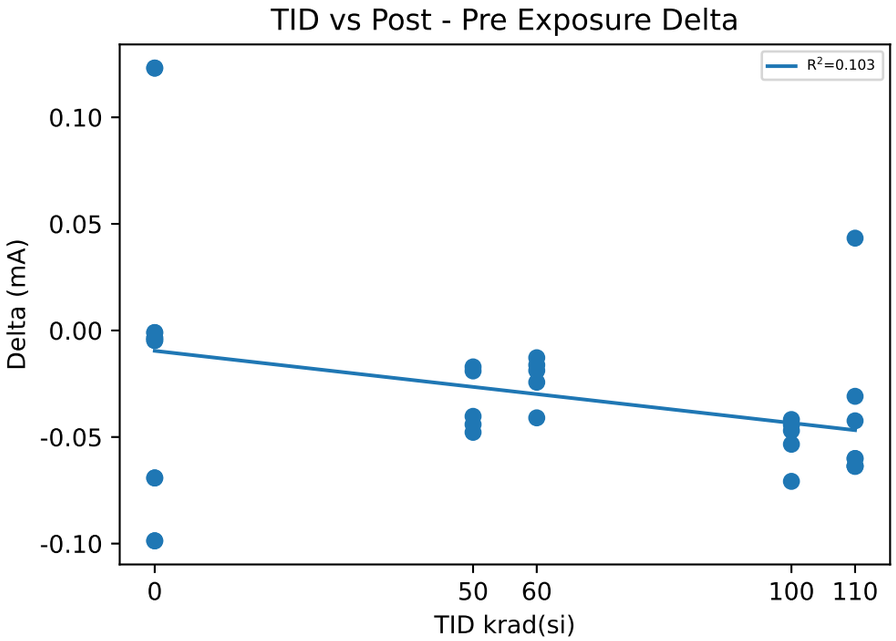
Device Test: 18.1 VIN_SHDN_CURR(IQ|ShutDown/VIN/3/3/0/0/90.9/634//1.8//pre/@VIN_SHDN_CURR)





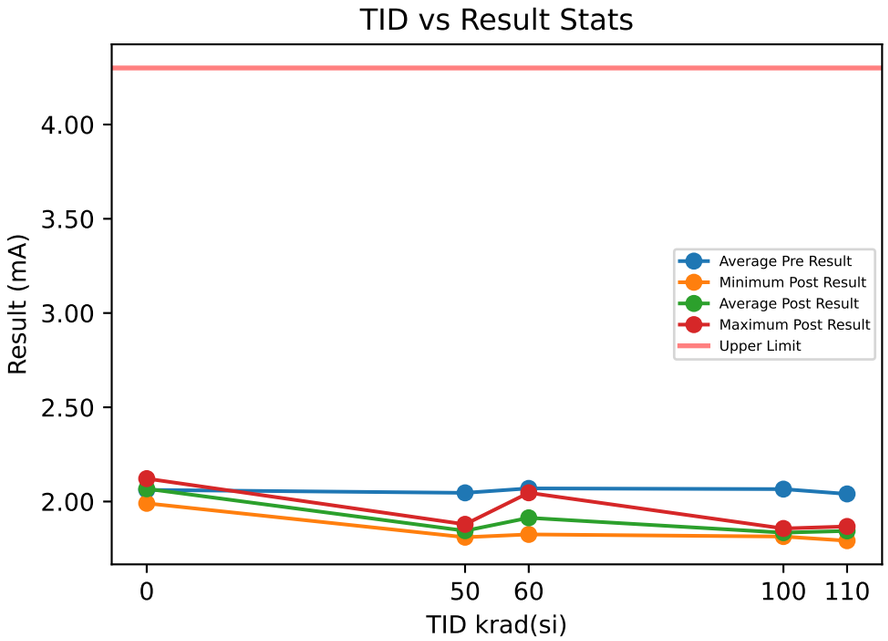
Test Results (Upper Limit = 8.5 (mA))

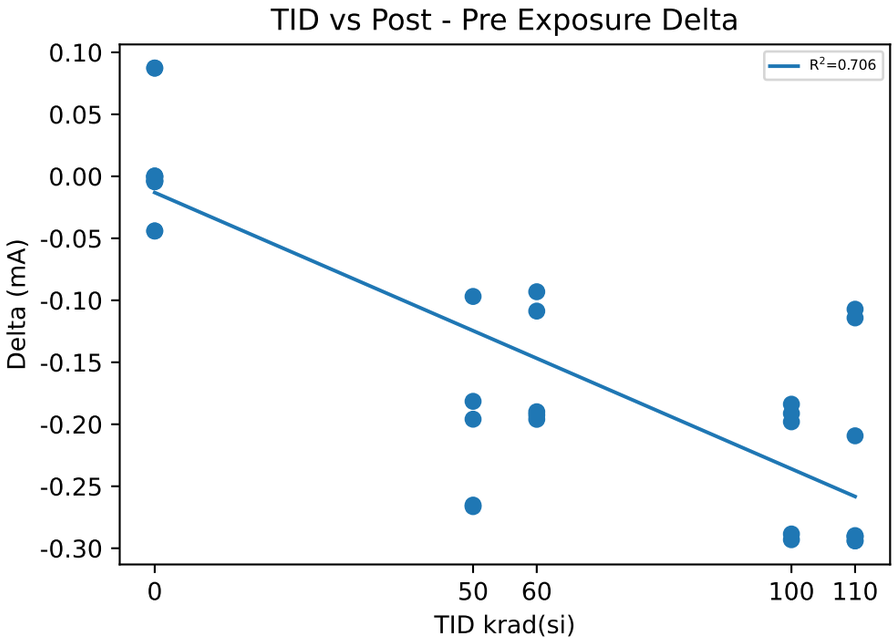
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.2092	5.2057	-0.0035
2	0	CU2	5.0941	5.0931	-0.001
3	0	CU3	5.1959	5.1912	-0.0047
11	50	Unbiased-50k	5.0578	5.0407	-0.0171
12	50	Unbiased-50k	5.1822	5.1419	-0.0403
13	50	Unbiased-50k	5.1956	5.1515	-0.0441
14	50	Unbiased-50k	5.2872	5.2682	-0.019
16	50	Unbiased-50k	5.228	5.1802	-0.0478
17	60	Biased-50k	5.256	5.2372	-0.0188
18	60	Biased-50k	5.2522	5.2279	-0.0243
19	60	Biased-50k	5.2686	5.2276	-0.041
20	60	Biased-50k	5.1931	5.1803	-0.0128
21	60	Biased-50k	5.1167	5.1005	-0.0162
24	100	Unbiased-100k	5.122	5.0686	-0.0534
25	100	Unbiased-100k	5.1291	5.0583	-0.0708
26	100	Unbiased-100k	5.0883	5.0465	-0.0418
27	100	Unbiased-100k	5.0734	5.0264	-0.047
28	100	Unbiased-100k	5.1594	5.1151	-0.0443
29	110	Biased-100k	5.1657	5.1233	-0.0424
30	110	Biased-100k	5.3017	5.2708	-0.0309
31	110	Biased-100k	5.155	5.0912	-0.0638
32	110	Biased-100k	5.1961	5.2394	0.0433
34	110	Biased-100k	5.1873	5.1237	-0.0636

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0941	5.1664	5.2092	0.062966	5.0931	5.1633	5.2057	0.061254	-0.0047	-0.0030667	-0.001	0.0018877
50	5.0578	5.1902	5.2872	0.084352	5.0407	5.1565	5.2682	0.08168	-0.0478	-0.03366	-0.0171	0.01451
60	5.1167	5.2173	5.2686	0.063351	5.1005	5.1947	5.2372	0.057166	-0.041	-0.02262	-0.0128	0.011101
100	5.0734	5.1144	5.1594	0.034136	5.0264	5.063	5.1151	0.03309	-0.0708	-0.05146	-0.0418	0.011643
110	5.155	5.2012	5.3017	0.058554	5.0912	5.1697	5.2708	0.07986	-0.0638	-0.03148	0.0433	0.044125

Device Test: 18.2 PVIN_SHDN_CURR(IQ|ShutDown/PVIN/3/3/0/0/90.9/634//1.8//pre/@PVIN_SHDN_CURR)





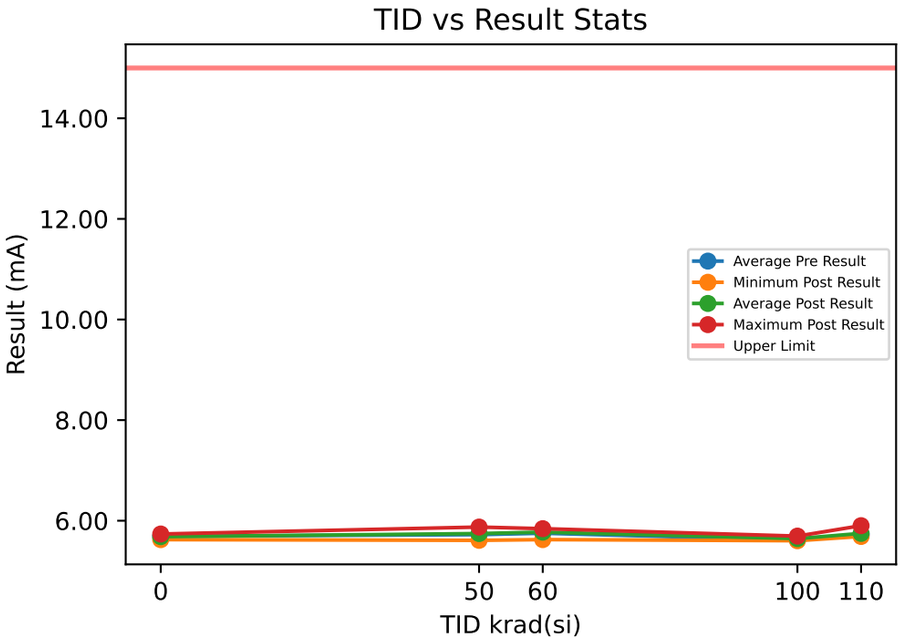
Test Results (Upper Limit = 4.3 (mA))

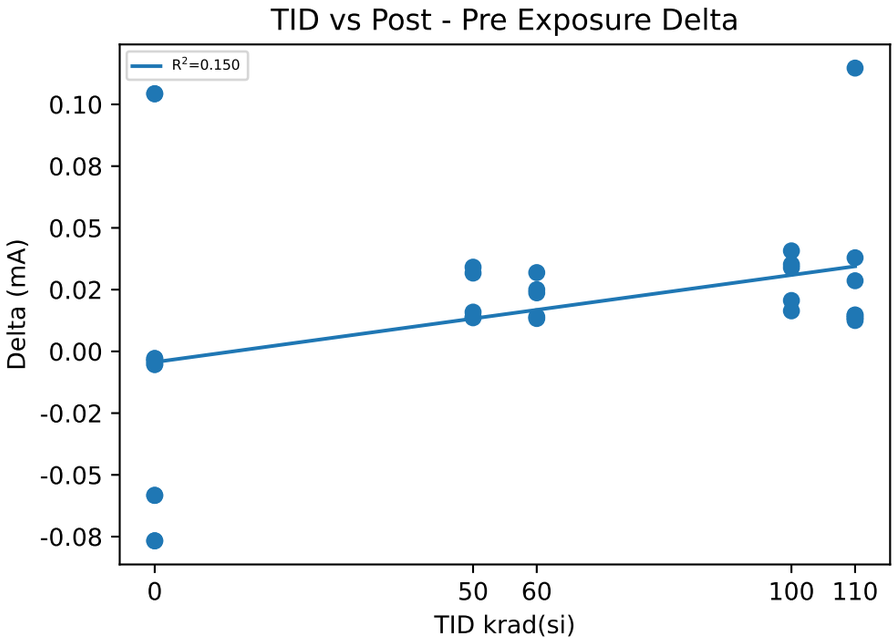
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0346	2.0303	-0.0043
2	0	CU2	2.0282	2.0284	0.0002
3	0	CU3	2.122	2.1215	-0.0005
11	50	Unbiased-50k	2.0216	1.8257	-0.1959
12	50	Unbiased-50k	2.1079	1.8427	-0.2652
13	50	Unbiased-50k	2.0479	1.8664	-0.1815
14	50	Unbiased-50k	1.976	1.8791	-0.0969
16	50	Unbiased-50k	2.077	1.8106	-0.2664
17	60	Biased-50k	2.121	2.0123	-0.1087
18	60	Biased-50k	2.0263	1.8303	-0.196
19	60	Biased-50k	2.0459	1.8534	-0.1925
20	60	Biased-50k	2.0154	1.8255	-0.1899
21	60	Biased-50k	2.1395	2.0464	-0.0931
24	100	Unbiased-100k	2.0229	1.8316	-0.1913
25	100	Unbiased-100k	2.1344	1.8413	-0.2931
26	100	Unbiased-100k	2.0283	1.8303	-0.198
27	100	Unbiased-100k	2.1027	1.8142	-0.2885
28	100	Unbiased-100k	2.0408	1.857	-0.1838
29	110	Biased-100k	2.049	1.8397	-0.2093
30	110	Biased-100k	1.9749	1.8677	-0.1072
31	110	Biased-100k	2.0819	1.7921	-0.2898
32	110	Biased-100k	1.9492	1.835	-0.1142
34	110	Biased-100k	2.1466	1.8526	-0.294

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0282	2.0616	2.122	0.052406	2.0284	2.0601	2.1215	0.053211	-0.0043	-0.0015333	0.0002	0.0024214
50	1.976	2.0461	2.1079	0.050724	1.8106	1.8449	1.8791	0.028204	-0.2664	-0.20118	-0.0969	0.070074
60	2.0154	2.0696	2.1395	0.056794	1.8255	1.9136	2.0464	0.10689	-0.196	-0.15604	-0.0931	0.050683
100	2.0229	2.0658	2.1344	0.049848	1.8142	1.8349	1.857	0.015731	-0.2931	-0.23094	-0.1838	0.054899
110	1.9492	2.0403	2.1466	0.080129	1.7921	1.8374	1.8677	0.028338	-0.294	-0.2029	-0.1072	0.090717

Device Test: 18.3 IQ_VIN(IQ|ActiveHSoffLSon/VIN/3/3/0/0/90.9/634//1.8//pre/@IQ_VIN)





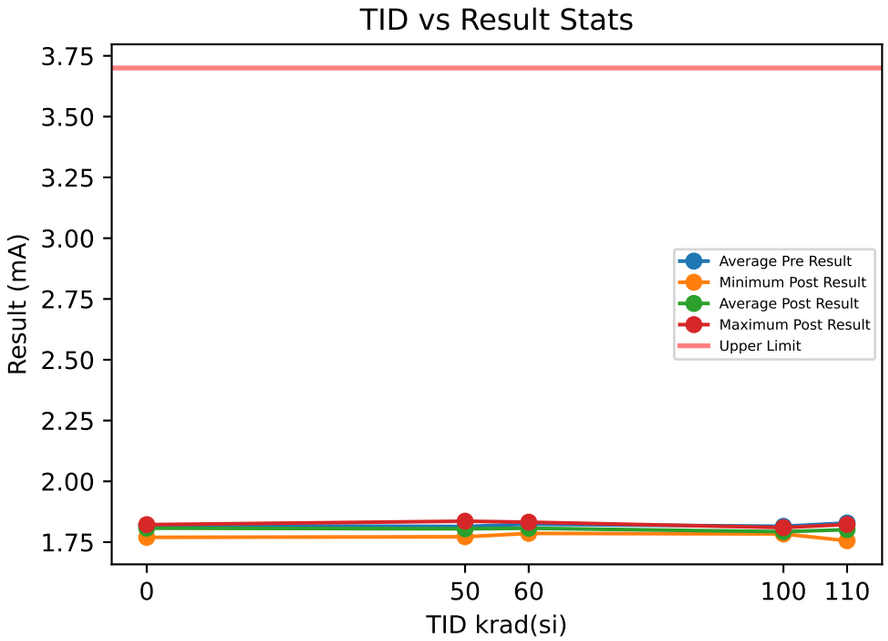
Test Results (Upper Limit = 15.0 (mA))

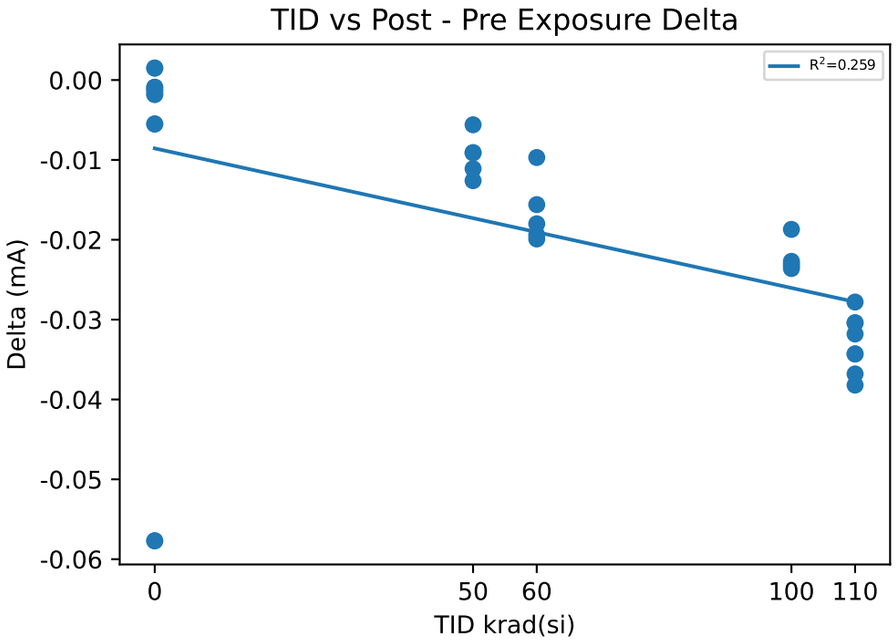
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7396	5.7357	-0.0039
2	0	CU2	5.6299	5.627	-0.0029
3	0	CU3	5.7008	5.6955	-0.0053
11	50	Unbiased-50k	5.576	5.6101	0.0341
12	50	Unbiased-50k	5.7056	5.7215	0.0159
13	50	Unbiased-50k	5.7323	5.7462	0.0139
14	50	Unbiased-50k	5.8421	5.8738	0.0317
16	50	Unbiased-50k	5.7589	5.7725	0.0136
17	60	Biased-50k	5.7806	5.7939	0.0133
18	60	Biased-50k	5.7986	5.8223	0.0237
19	60	Biased-50k	5.8281	5.8421	0.014
20	60	Biased-50k	5.7494	5.7813	0.0319
21	60	Biased-50k	5.5996	5.6246	0.025
24	100	Unbiased-100k	5.6251	5.6457	0.0206
25	100	Unbiased-100k	5.6354	5.6518	0.0164
26	100	Unbiased-100k	5.5915	5.6267	0.0352
27	100	Unbiased-100k	5.5617	5.6024	0.0407
28	100	Unbiased-100k	5.6603	5.6942	0.0339
29	110	Biased-100k	5.6586	5.6872	0.0286
30	110	Biased-100k	5.8635	5.9014	0.0379
31	110	Biased-100k	5.677	5.6895	0.0125
32	110	Biased-100k	5.7359	5.8506	0.1147
34	110	Biased-100k	5.7	5.7135	0.0135

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6299	5.6901	5.7396	0.055627	5.627	5.6861	5.7357	0.054961	-0.0053	-0.0040333	-0.0029	0.0012055
50	5.576	5.723	5.8421	0.096788	5.6101	5.7448	5.8738	0.094996	0.0136	0.02184	0.0341	0.01017
60	5.5996	5.7513	5.8281	0.089457	5.6246	5.7728	5.8421	0.086217	0.0133	0.02158	0.0319	0.0078852
100	5.5617	5.6148	5.6603	0.038611	5.6024	5.6442	5.6942	0.033961	0.0164	0.02936	0.0407	0.010344
110	5.6586	5.727	5.8635	0.081577	5.6872	5.7684	5.9014	0.10035	0.0125	0.04144	0.1147	0.042316

Device Test: 18.4 IQ_PVIN(IQ|ActiveHSoffLSon/PVIN/3/3/0/0/90.9/634//1.8//pre/@IQ_PVIN)





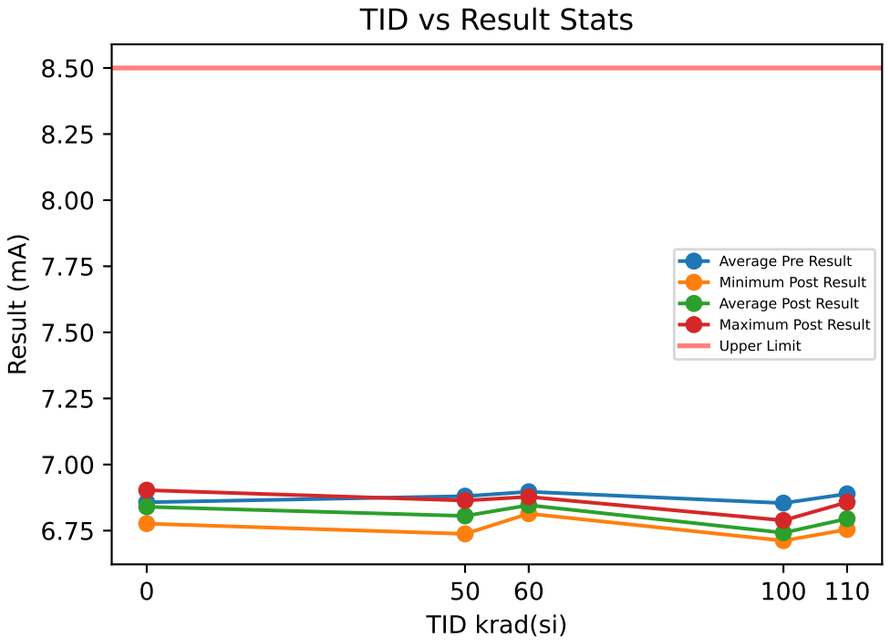
Test Results (Upper Limit = 3.7 (mA))

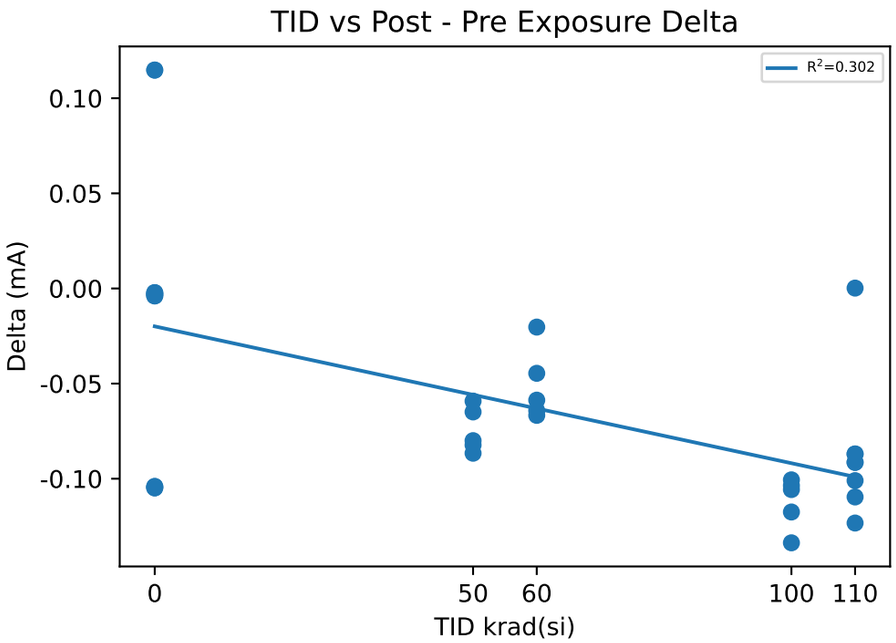
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.8274	1.8219	-0.0055
2	0	CU2	1.8169	1.8151	-0.0018
3	0	CU3	1.8106	1.8097	-0.0009
11	50	Unbiased-50k	1.8016	1.789	-0.0126
12	50	Unbiased-50k	1.8148	1.8037	-0.0111
13	50	Unbiased-50k	1.8323	1.8232	-0.0091
14	50	Unbiased-50k	1.8452	1.8361	-0.0091
16	50	Unbiased-50k	1.7776	1.772	-0.0056
17	60	Biased-50k	1.8264	1.8084	-0.018
18	60	Biased-50k	1.8112	1.7913	-0.0199
19	60	Biased-50k	1.833	1.8174	-0.0156
20	60	Biased-50k	1.8053	1.7859	-0.0194
21	60	Biased-50k	1.8418	1.8321	-0.0097
24	100	Unbiased-100k	1.8106	1.7876	-0.023
25	100	Unbiased-100k	1.813	1.7897	-0.0233
26	100	Unbiased-100k	1.8165	1.7938	-0.0227
27	100	Unbiased-100k	1.8072	1.7836	-0.0236
28	100	Unbiased-100k	1.8284	1.8097	-0.0187
29	110	Biased-100k	1.8357	1.7975	-0.0382
30	110	Biased-100k	1.8504	1.8226	-0.0278
31	110	Biased-100k	1.7926	1.7558	-0.0368
32	110	Biased-100k	1.822	1.7902	-0.0318
34	110	Biased-100k	1.8432	1.8089	-0.0343

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8106	1.8183	1.8274	0.008487	1.8097	1.8156	1.8219	0.0061134	-0.0055	-0.0027333	-0.0009	0.0024379
50	1.7776	1.8143	1.8452	0.026397	1.772	1.8048	1.8361	0.025714	-0.0126	-0.0095	-0.0056	0.0026315
60	1.8053	1.8235	1.8418	0.015133	1.7859	1.807	1.8321	0.01892	-0.0199	-0.01652	-0.0097	0.0041614
100	1.8072	1.8151	1.8284	0.0081534	1.7836	1.7929	1.8097	0.010098	-0.0236	-0.02226	-0.0187	0.0020182
110	1.7926	1.8288	1.8504	0.022794	1.7558	1.795	1.8226	0.025104	-0.0382	-0.03378	-0.0278	0.0041415

Device Test: 19.1 VIN_SHDN_CURR(IQ|ShutDown/VIN/7/7/0/0/90.9/634//1.8//pre/@VIN_SHDN_CURR)





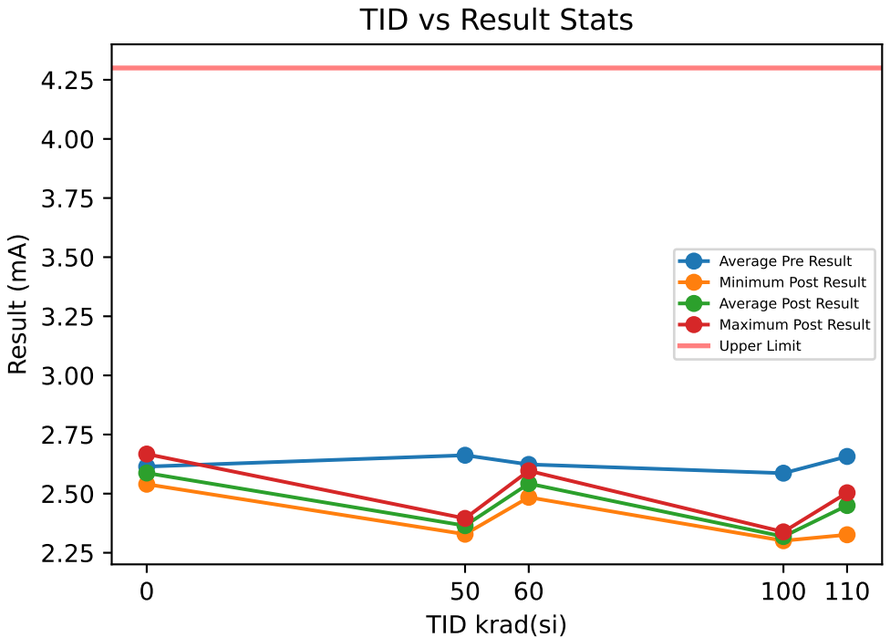
Test Results (Upper Limit = 8.5 (mA))

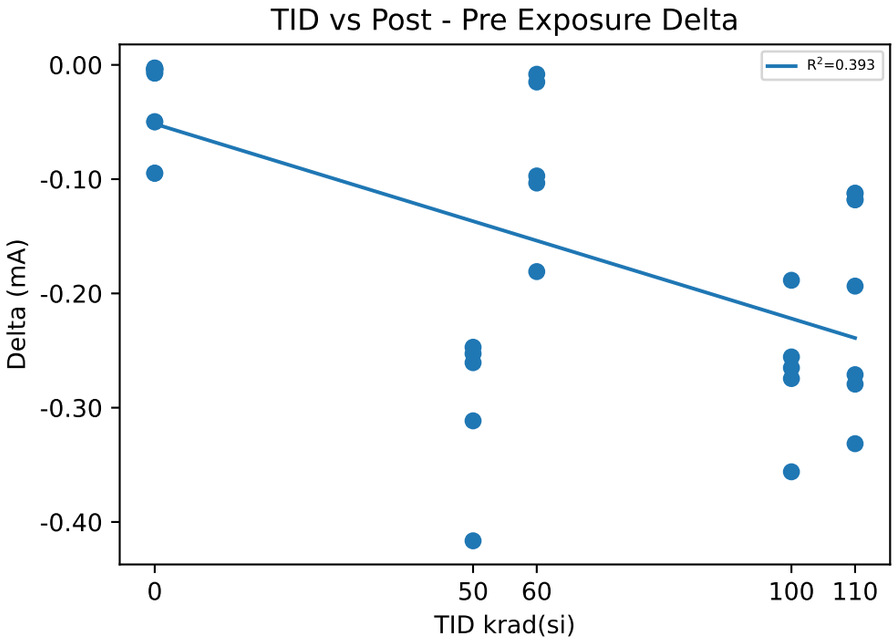
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.9069	6.903	-0.0039
2	0	CU2	6.7836	6.7806	-0.003
3	0	CU3	6.8812	6.879	-0.0022
11	50	Unbiased-50k	6.8177	6.7377	-0.08
12	50	Unbiased-50k	6.8744	6.8152	-0.0592
13	50	Unbiased-50k	6.8697	6.7874	-0.0823
14	50	Unbiased-50k	6.9287	6.8638	-0.0649
16	50	Unbiased-50k	6.9108	6.8242	-0.0866
17	60	Biased-50k	6.9445	6.8778	-0.0667
18	60	Biased-50k	6.9184	6.8542	-0.0642
19	60	Biased-50k	6.8823	6.8236	-0.0587
20	60	Biased-50k	6.8813	6.861	-0.0203
21	60	Biased-50k	6.8588	6.8142	-0.0446
24	100	Unbiased-100k	6.8554	6.7379	-0.1175
25	100	Unbiased-100k	6.8562	6.7225	-0.1337
26	100	Unbiased-100k	6.8175	6.7118	-0.1057
27	100	Unbiased-100k	6.8492	6.7486	-0.1006
28	100	Unbiased-100k	6.8923	6.7887	-0.1036
29	110	Biased-100k	6.8975	6.7879	-0.1096
30	110	Biased-100k	6.9438	6.8428	-0.101
31	110	Biased-100k	6.8776	6.7543	-0.1233
32	110	Biased-100k	6.8572	6.8574	0.0002
34	110	Biased-100k	6.8685	6.7771	-0.0914

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7836	6.8572	6.9069	0.06505	6.7806	6.8542	6.903	0.064859	-0.0039	-0.0030333	-0.0022	0.00085049
50	6.8177	6.8803	6.9287	0.042833	6.7377	6.8057	6.8638	0.046816	-0.0866	-0.0746	-0.0592	0.011871
60	6.8588	6.8971	6.9445	0.034044	6.8142	6.8462	6.8778	0.026535	-0.0667	-0.0509	-0.0203	0.019127
100	6.8175	6.8541	6.8923	0.026594	6.7118	6.7419	6.7887	0.029722	-0.1337	-0.11222	-0.1006	0.013612
110	6.8572	6.8889	6.9438	0.034047	6.7543	6.8039	6.8574	0.044187	-0.1233	-0.08502	0.0002	0.049061

Device Test: 19.2 PVIN_SHDN_CURR(IQ|ShutDown/PVIN/7/7/0/0/90.9/634//1.8//pre/@PVIN_SHDN_CURR)





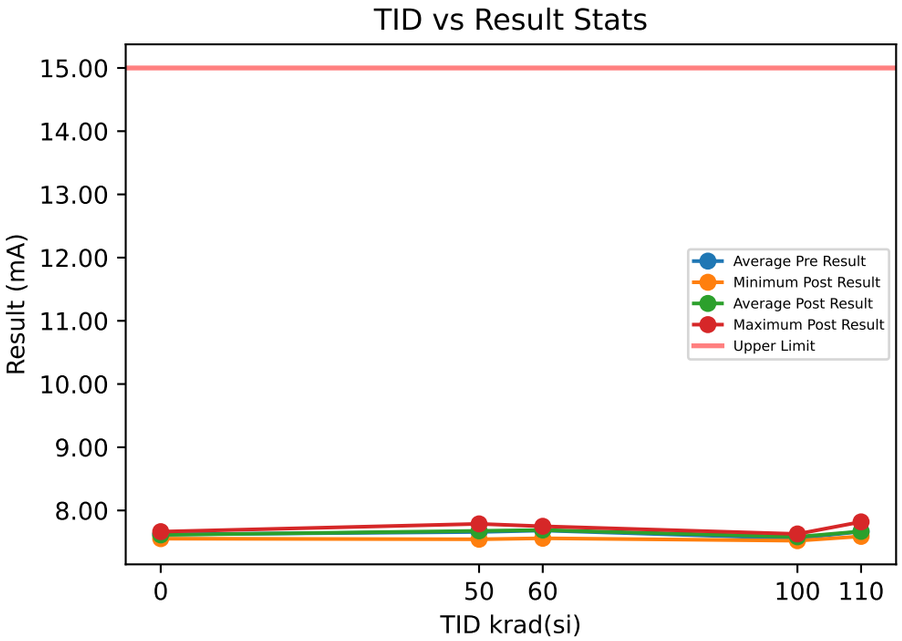
Test Results (Upper Limit = 4.3 (mA))

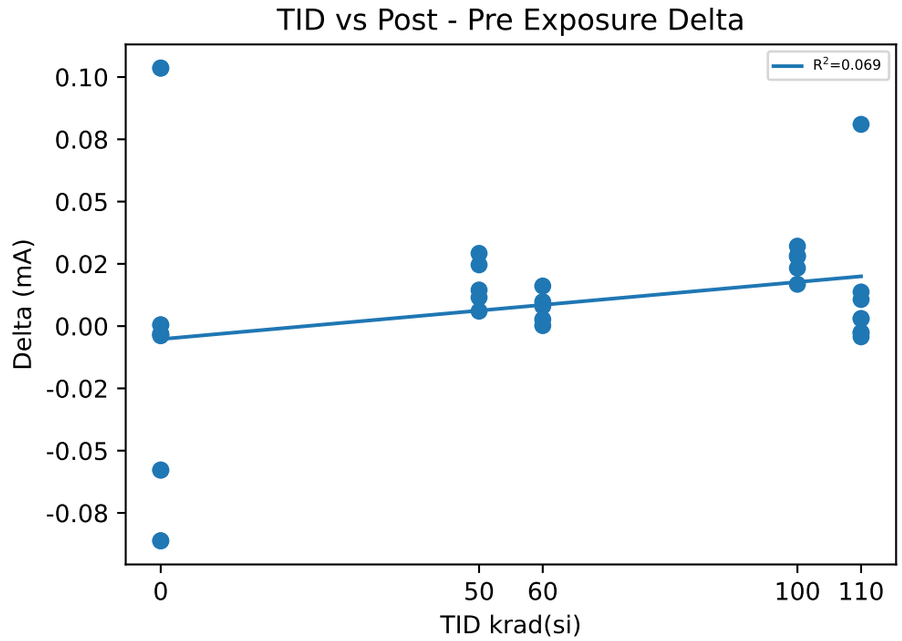
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5896	2.5824	-0.0072
2	0	CU2	2.5833	2.5797	-0.0036
3	0	CU3	2.6702	2.6674	-0.0028
11	50	Unbiased-50k	2.8117	2.3952	-0.4165
12	50	Unbiased-50k	2.5755	2.3284	-0.2471
13	50	Unbiased-50k	2.6072	2.3545	-0.2527
14	50	Unbiased-50k	2.6278	2.3672	-0.2606
16	50	Unbiased-50k	2.6892	2.3777	-0.3115
17	60	Biased-50k	2.7424	2.5615	-0.1809
18	60	Biased-50k	2.588	2.4846	-0.1034
19	60	Biased-50k	2.6035	2.5063	-0.0972
20	60	Biased-50k	2.5785	2.5635	-0.015
21	60	Biased-50k	2.6048	2.5966	-0.0082
24	100	Unbiased-100k	2.5769	2.3118	-0.2651
25	100	Unbiased-100k	2.6821	2.326	-0.3561
26	100	Unbiased-100k	2.5042	2.3157	-0.1885
27	100	Unbiased-100k	2.5754	2.3009	-0.2745
28	100	Unbiased-100k	2.5939	2.3383	-0.2556
29	110	Biased-100k	2.5972	2.3261	-0.2711
30	110	Biased-100k	2.7554	2.4239	-0.3315
31	110	Biased-100k	2.7169	2.4375	-0.2794
32	110	Biased-100k	2.6006	2.407	-0.1936
34	110	Biased-100k	2.616	2.498	-0.118

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5833	2.6144	2.6702	0.048456	2.5797	2.6098	2.6674	0.049872	-0.0072	-0.0045333	-0.0028	0.0023438
50	2.5755	2.6623	2.8117	0.09328	2.3284	2.3646	2.3952	0.025136	-0.4165	-0.29768	-0.2471	0.071179
60	2.5785	2.6234	2.7424	0.067402	2.4846	2.5425	2.5966	0.045803	-0.1809	-0.08094	-0.0082	0.071414
100	2.5042	2.5865	2.6821	0.063606	2.3009	2.3185	2.3383	0.014237	-0.3561	-0.26796	-0.1885	0.059763
110	2.5972	2.6572	2.7554	0.073669	2.3261	2.4185	2.498	0.062009	-0.3315	-0.23872	-0.118	0.083547

Device Test: 19.3 IQ_VIN(IQ|ActiveHSoffLSon/VIN/7/7/0/0/90.9/634//1.8//pre/@IQ_VIN)





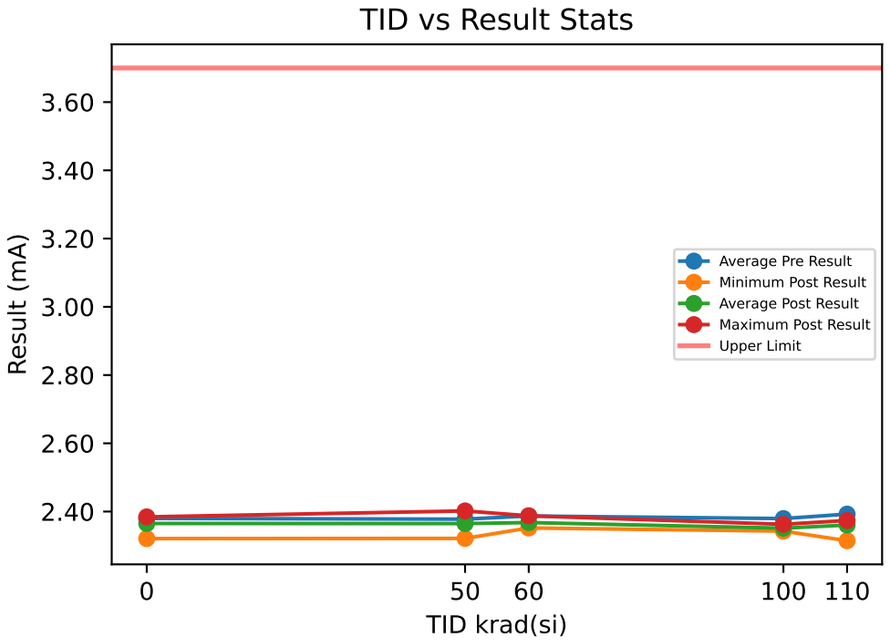
Test Results (Upper Limit = 15.0 (mA))

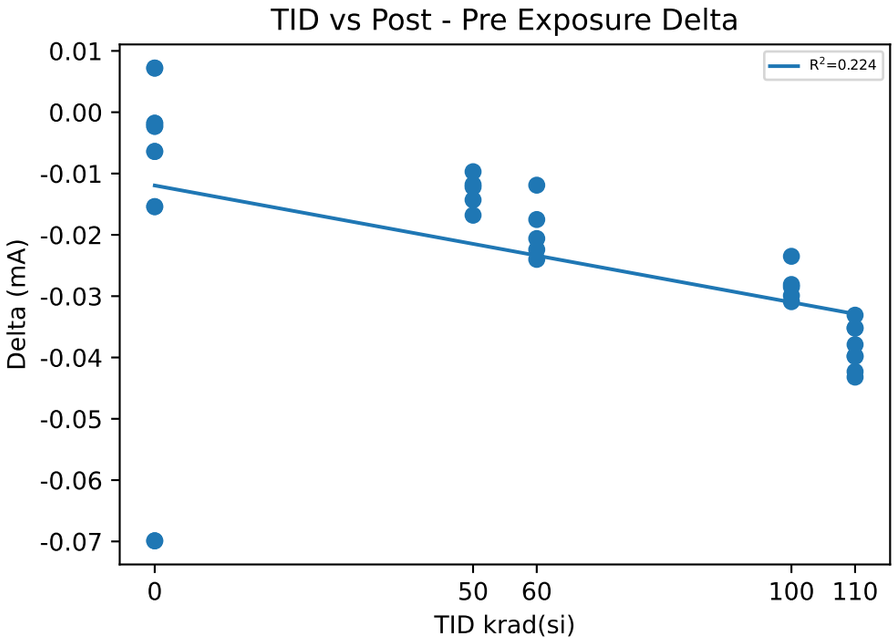
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	7.6642	7.6647	0.0005
2	0	CU2	7.5587	7.5556	-0.0031
3	0	CU3	7.6399	7.6361	-0.0038
11	50	Unbiased-50k	7.515	7.5442	0.0292
12	50	Unbiased-50k	7.6339	7.6484	0.0145
13	50	Unbiased-50k	7.6802	7.6917	0.0115
14	50	Unbiased-50k	7.763	7.7876	0.0246
16	50	Unbiased-50k	7.7062	7.7122	0.006
17	60	Biased-50k	7.6945	7.6972	0.0027
18	60	Biased-50k	7.7414	7.7494	0.008
19	60	Biased-50k	7.7484	7.7486	0.0002
20	60	Biased-50k	7.6793	7.6954	0.0161
21	60	Biased-50k	7.5499	7.5597	0.0098
24	100	Unbiased-100k	7.563	7.5798	0.0168
25	100	Unbiased-100k	7.5926	7.6159	0.0233
26	100	Unbiased-100k	7.5424	7.5703	0.0279
27	100	Unbiased-100k	7.4891	7.5212	0.0321
28	100	Unbiased-100k	7.6	7.6283	0.0283
29	110	Biased-100k	7.5762	7.5899	0.0137
30	110	Biased-100k	7.8085	7.8192	0.0107
31	110	Biased-100k	7.6349	7.6306	-0.0043
32	110	Biased-100k	7.6749	7.7559	0.081
34	110	Biased-100k	7.6388	7.6362	-0.0026

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.5587	7.6209	7.6642	0.055248	7.5556	7.6188	7.6647	0.05657	-0.0038	-0.0021333	0.0005	0.0023072
50	7.515	7.6597	7.763	0.09335	7.5442	7.6768	7.7876	0.08964	0.006	0.01716	0.0292	0.009539
60	7.5499	7.6827	7.7484	0.07992	7.5597	7.6901	7.7494	0.077494	0.0002	0.00736	0.0161	0.0062396
100	7.4891	7.5574	7.6	0.044652	7.5212	7.5831	7.6283	0.042206	0.0168	0.02568	0.0321	0.0058636
110	7.5762	7.6667	7.8085	0.086825	7.5899	7.6864	7.8192	0.096711	-0.0043	0.0197	0.081	0.035171

Device Test: 19.4 IQ_PVIN(IQ|ActiveHSoffLSon/PVIN/7/7/0/0/90.9/634//1.8//pre/@IQ_PVIN)





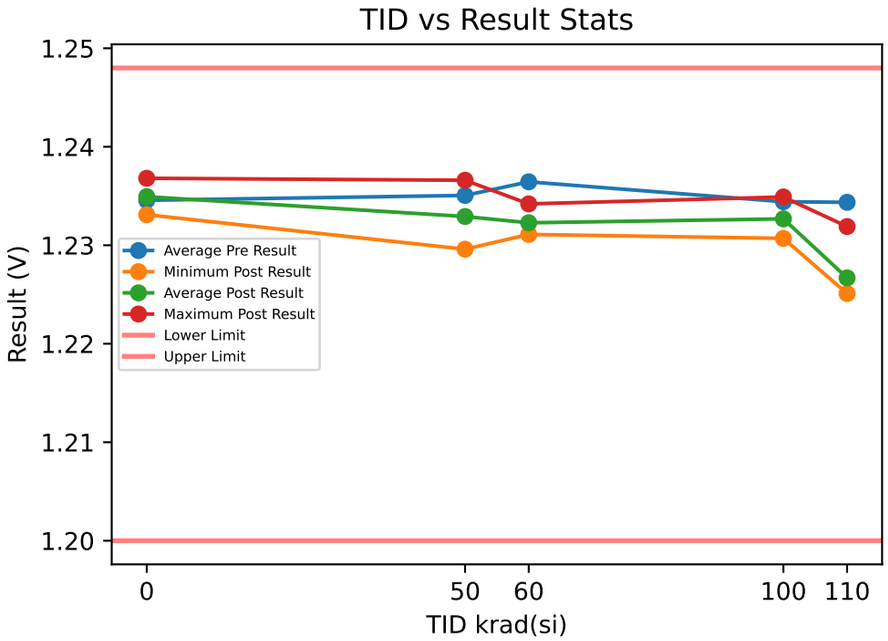
Test Results (Upper Limit = 3.7 (mA))

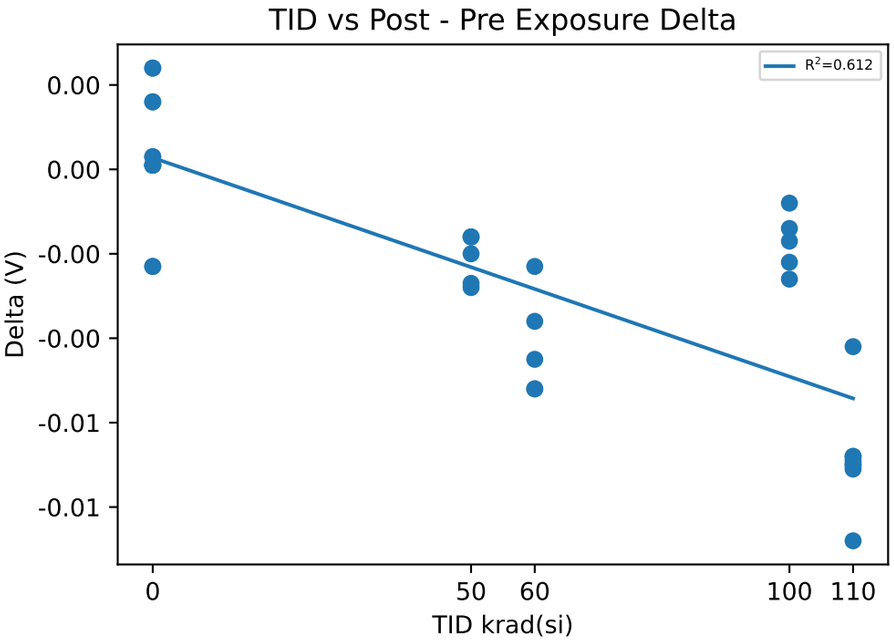
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3907	2.3843	-0.0064
2	0	CU2	2.3715	2.3692	-0.0023
3	0	CU3	2.3772	2.3754	-0.0018
11	50	Unbiased-50k	2.3639	2.3471	-0.0168
12	50	Unbiased-50k	2.3796	2.3653	-0.0143
13	50	Unbiased-50k	2.4006	2.3884	-0.0122
14	50	Unbiased-50k	2.4136	2.4018	-0.0118
16	50	Unbiased-50k	2.331	2.3213	-0.0097
17	60	Biased-50k	2.3829	2.3623	-0.0206
18	60	Biased-50k	2.3796	2.3556	-0.024
19	60	Biased-50k	2.3986	2.3811	-0.0175
20	60	Biased-50k	2.3743	2.3519	-0.0224
21	60	Biased-50k	2.3994	2.3875	-0.0119
24	100	Unbiased-100k	2.3725	2.3426	-0.0299
25	100	Unbiased-100k	2.3797	2.3488	-0.0309
26	100	Unbiased-100k	2.384	2.3559	-0.0281
27	100	Unbiased-100k	2.3748	2.3463	-0.0285
28	100	Unbiased-100k	2.3861	2.3626	-0.0235
29	110	Biased-100k	2.4045	2.3613	-0.0432
30	110	Biased-100k	2.4021	2.369	-0.0331
31	110	Biased-100k	2.3568	2.3145	-0.0423
32	110	Biased-100k	2.3901	2.3522	-0.0379
34	110	Biased-100k	2.409	2.3692	-0.0398

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3715	2.3798	2.3907	0.0098605	2.3692	2.3763	2.3843	0.0075901	-0.0064	-0.0035	-0.0018	0.0025239
50	2.331	2.3777	2.4136	0.032358	2.3213	2.3648	2.4018	0.032139	-0.0168	-0.01296	-0.0097	0.0026969
60	2.3743	2.387	2.3994	0.011415	2.3519	2.3677	2.3875	0.015786	-0.024	-0.01928	-0.0119	0.0047799
100	2.3725	2.3794	2.3861	0.0058075	2.3426	2.3512	2.3626	0.0079964	-0.0309	-0.02818	-0.0235	0.0028446
110	2.3568	2.3925	2.409	0.021146	2.3145	2.3532	2.3692	0.022748	-0.0432	-0.03926	-0.0331	0.0040265

Device Test: 21.1 VREFCAP(REF|REFCAP/REFCAP/3/3/0/0/90.9/634//1.8//25C/@VREFCAP)





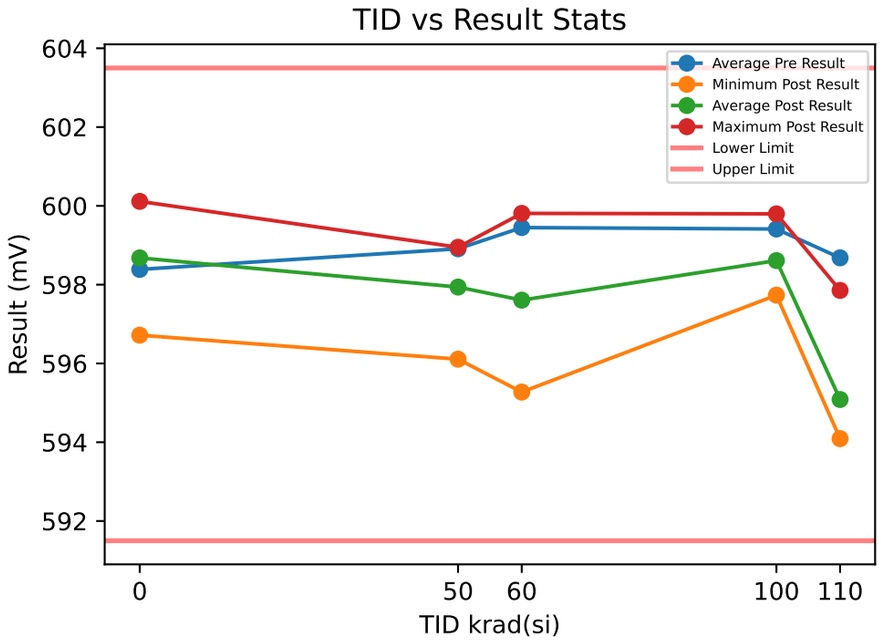
Test Results (Lower Limit = 1.2, Upper Limit = 1.248 (V))

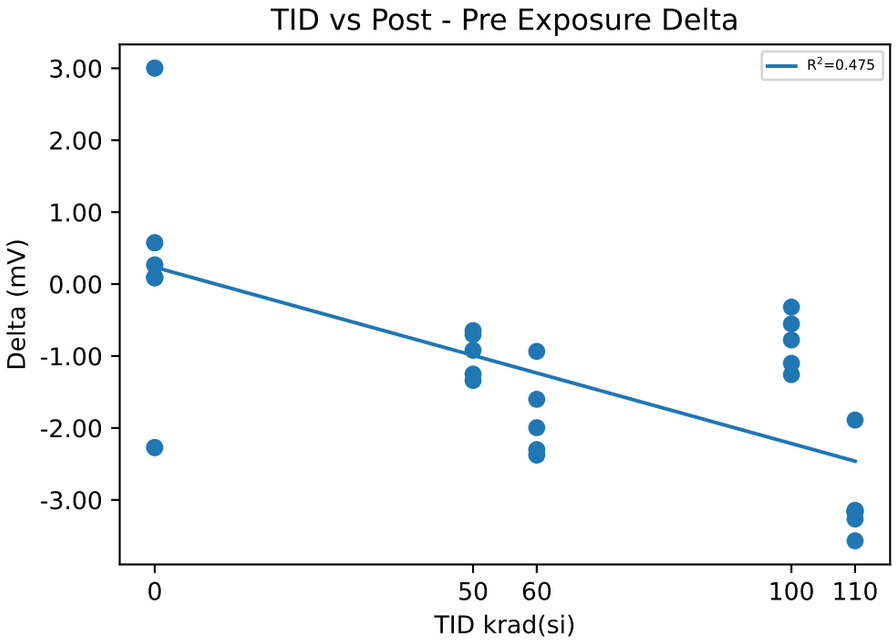
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.2352	1.2353	0.0001
2	0	CU2	1.233	1.2331	0.0001
3	0	CU3	1.2355	1.2358	0.0003
11	50	Unbiased-50k	1.2323	1.2296	-0.0027
12	50	Unbiased-50k	1.2358	1.233	-0.0028
13	50	Unbiased-50k	1.2382	1.2366	-0.0016
14	50	Unbiased-50k	1.2344	1.2328	-0.0016
16	50	Unbiased-50k	1.2346	1.2326	-0.002
17	60	Biased-50k	1.2367	1.2331	-0.0036
18	60	Biased-50k	1.2364	1.2312	-0.0052
19	60	Biased-50k	1.2356	1.2311	-0.0045
20	60	Biased-50k	1.237	1.2318	-0.0052
21	60	Biased-50k	1.2365	1.2342	-0.0023
24	100	Unbiased-100k	1.2339	1.2317	-0.0022
25	100	Unbiased-100k	1.2348	1.2331	-0.0017
26	100	Unbiased-100k	1.2375	1.2349	-0.0026
27	100	Unbiased-100k	1.2315	1.2307	-0.0008
28	100	Unbiased-100k	1.2344	1.233	-0.0014
29	110	Biased-100k	1.2352	1.2283	-0.0069
30	110	Biased-100k	1.2361	1.2319	-0.0042
31	110	Biased-100k	1.2322	1.2251	-0.0071
32	110	Biased-100k	1.2362	1.2274	-0.0088
34	110	Biased-100k	1.2321	1.2253	-0.0068

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.233	1.2346	1.2355	0.001365	1.2331	1.2347	1.2358	0.0014364	0.0001	0.00016667	0.0003	0.00011547
50	1.2323	1.2351	1.2382	0.0021606	1.2296	1.2329	1.2366	0.0024844	-0.0028	-0.00214	-0.0016	0.00058138
60	1.2356	1.2364	1.237	0.00052249	1.2311	1.2323	1.2342	0.0013368	-0.0052	-0.00416	-0.0023	0.00123
100	1.2315	1.2344	1.2375	0.0021464	1.2307	1.2327	1.2349	0.0015881	-0.0026	-0.00174	-0.0008	0.00069857
110	1.2321	1.2344	1.2362	0.002055	1.2251	1.2276	1.2319	0.0027641	-0.0088	-0.00676	-0.0042	0.0016471

Device Test: 21.2 VREF_25C(REF|VREF/VREF1/3/3/0/0/90.9/634//1.8//25C/@VREF_25C)





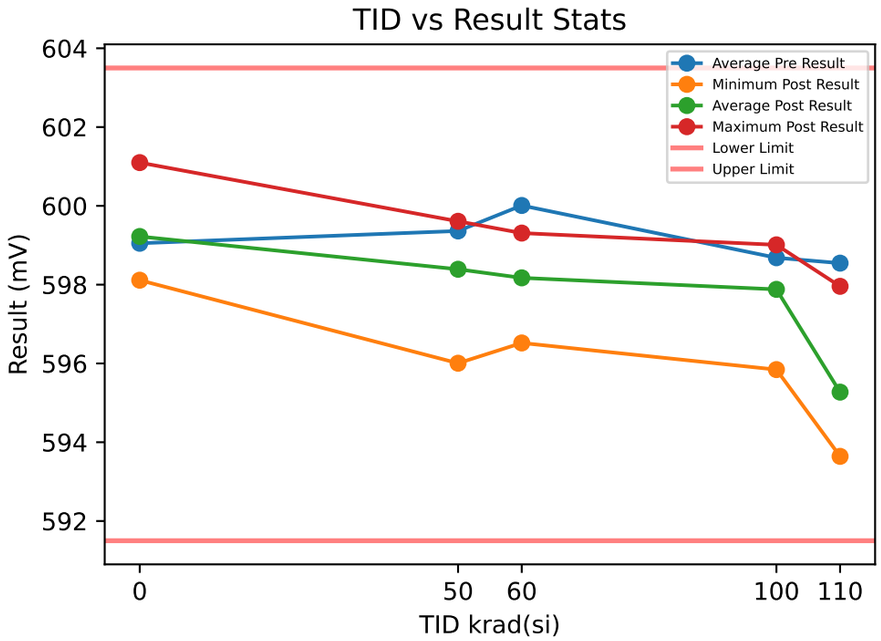
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

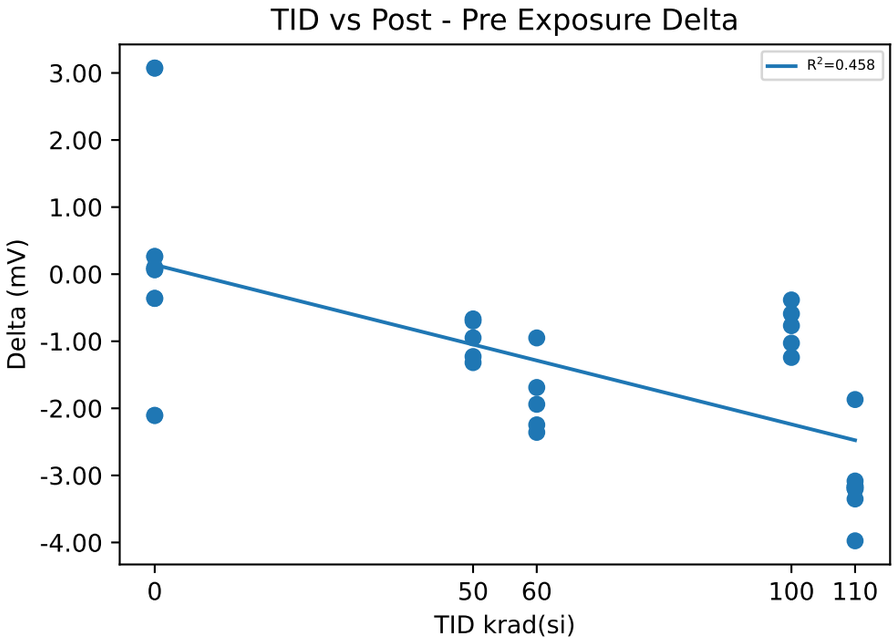
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.54	599.63	0.0941
2	0	CU2	596.63	596.72	0.0878
3	0	CU3	598.99	599.25	0.2661
11	50	Unbiased-50k	597.36	596.11	-1.2508
12	50	Unbiased-50k	600.29	598.95	-1.3392
13	50	Unbiased-50k	599.47	598.83	-0.6457
14	50	Unbiased-50k	598.72	598.02	-0.7015
16	50	Unbiased-50k	598.71	597.79	-0.9202
17	60	Biased-50k	599.76	598.16	-1.6014
18	60	Biased-50k	597.65	595.27	-2.3767
19	60	Biased-50k	599.5	597.5	-1.996
20	60	Biased-50k	599.59	597.29	-2.3001
21	60	Biased-50k	600.74	599.81	-0.9349
24	100	Unbiased-100k	598.83	597.73	-1.1007
25	100	Unbiased-100k	599.52	598.75	-0.7765
26	100	Unbiased-100k	601.06	599.8	-1.2579
27	100	Unbiased-100k	598.11	597.79	-0.3197
28	100	Unbiased-100k	599.54	598.98	-0.5534
29	110	Biased-100k	599.04	595.9	-3.1447
30	110	Biased-100k	599.74	597.85	-1.8897
31	110	Biased-100k	597.51	594.24	-3.2653
32	110	Biased-100k	599.85	596.28	-3.5684
34	110	Biased-100k	597.26	594.11	-3.1502

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.63	598.39	599.54	1.5447	596.72	598.54	599.63	1.5846	0.0878	0.14933	0.2661	0.10117
50	597.36	598.91	600.29	1.0836	596.11	597.94	598.95	1.1392	-1.3392	-0.97148	-0.6457	0.3142
60	597.65	599.45	600.74	1.1216	595.27	597.61	599.81	1.636	-2.3767	-1.8418	-0.9349	0.59165
100	598.11	599.41	601.06	1.0896	597.73	598.61	599.8	0.86651	-1.2579	-0.80164	-0.3197	0.38475
110	597.26	598.68	599.85	1.2264	594.11	595.68	597.85	1.5543	-3.5684	-3.0037	-1.8897	0.64608

Device Test: 21.3 VREF_25C(REF|VREF/VREF2/3/3/0/0/90.9/634//1.8//25C/@VREF_25C)





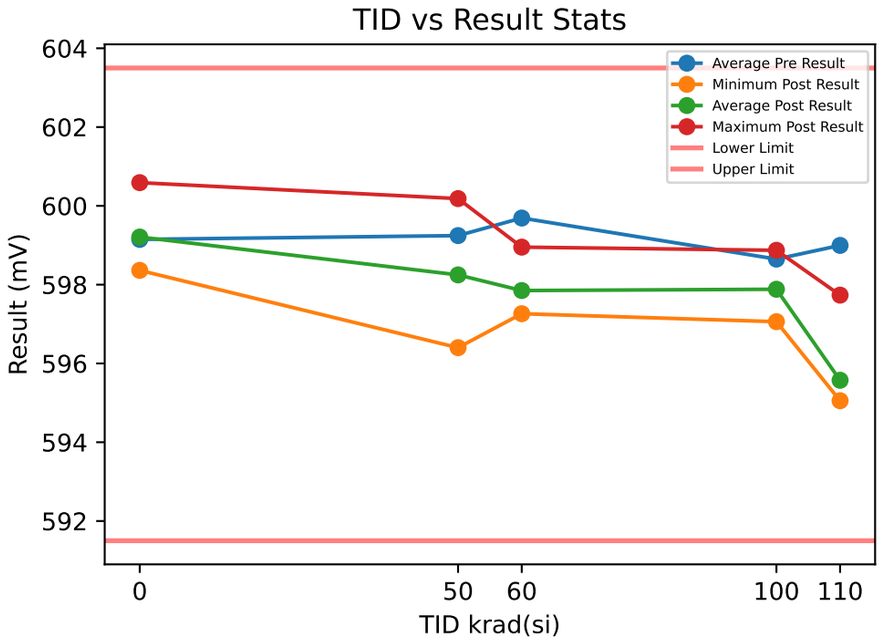
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

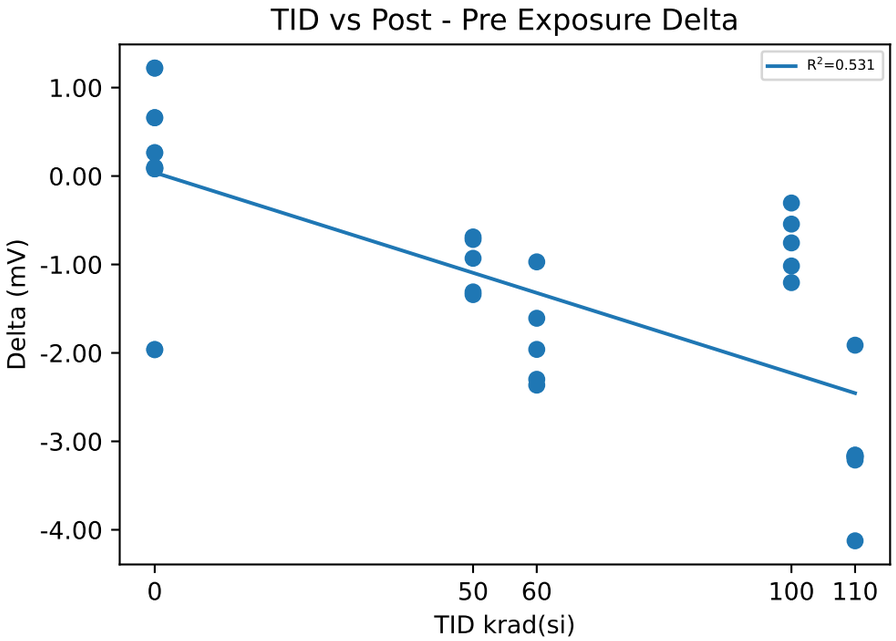
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.03	598.12	0.0961
2	0	CU2	598.47	598.54	0.0671
3	0	CU3	600.65	600.92	0.2633
11	50	Unbiased-50k	597.23	596.01	-1.2282
12	50	Unbiased-50k	599.6	598.29	-1.3185
13	50	Unbiased-50k	599.9	599.24	-0.6669
14	50	Unbiased-50k	599.51	598.82	-0.698
16	50	Unbiased-50k	600.56	599.61	-0.9482
17	60	Biased-50k	600.38	598.69	-1.6893
18	60	Biased-50k	598.88	596.52	-2.3582
19	60	Biased-50k	599.93	597.99	-1.9402
20	60	Biased-50k	600.6	598.36	-2.2462
21	60	Biased-50k	600.26	599.31	-0.9504
24	100	Unbiased-100k	598.85	597.82	-1.028
25	100	Unbiased-100k	599.78	599.01	-0.7675
26	100	Unbiased-100k	599.41	598.17	-1.2412
27	100	Unbiased-100k	596.23	595.84	-0.3843
28	100	Unbiased-100k	599.15	598.56	-0.5906
29	110	Biased-100k	598.49	595.41	-3.0839
30	110	Biased-100k	599.83	597.96	-1.8691
31	110	Biased-100k	596.99	593.64	-3.3516
32	110	Biased-100k	599.27	595.29	-3.9754
34	110	Biased-100k	598.15	594.99	-3.1643

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.03	599.05	600.65	1.405	598.12	599.19	600.92	1.5066	0.0671	0.14217	0.2633	0.1059
50	597.23	599.36	600.56	1.2583	596.01	598.39	599.61	1.4214	-1.3185	-0.97196	-0.6669	0.29767
60	598.88	600.01	600.6	0.67763	596.52	598.17	599.31	1.0433	-2.3582	-1.8369	-0.9504	0.56072
100	596.23	598.68	599.78	1.4141	595.84	597.88	599.01	1.2222	-1.2412	-0.80232	-0.3843	0.34071
110	596.99	598.55	599.83	1.0875	593.64	595.46	597.96	1.5653	-3.9754	-3.0889	-1.8691	0.76624

Device Test: 21.4 VREF_25C(REF|VREF/VREF3/3/3/0/0/90.9/634//1.8//25C/@VREF_25C)





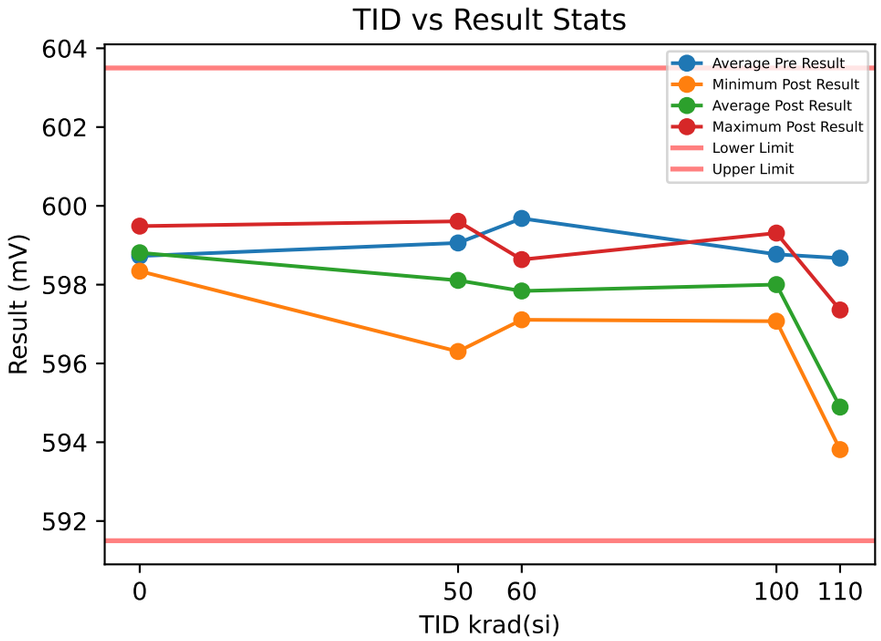
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

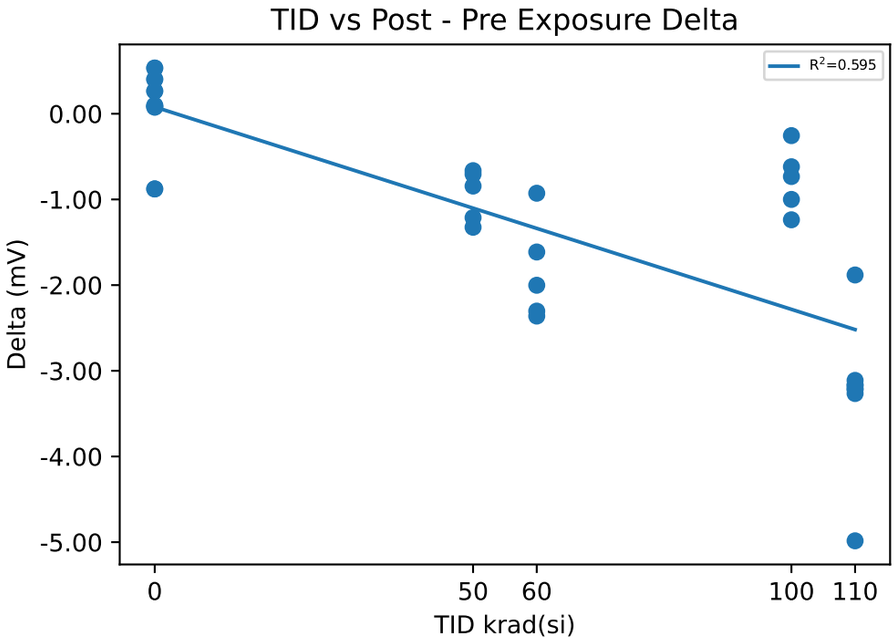
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.84	598.94	0.0965
2	0	CU2	598.28	598.36	0.0812
3	0	CU3	600.33	600.59	0.2637
11	50	Unbiased-50k	597.71	596.4	-1.3105
12	50	Unbiased-50k	599.23	597.89	-1.3407
13	50	Unbiased-50k	600.9	600.18	-0.7171
14	50	Unbiased-50k	599.23	598.54	-0.6888
16	50	Unbiased-50k	599.15	598.22	-0.9303
17	60	Biased-50k	599.01	597.4	-1.6083
18	60	Biased-50k	599.63	597.26	-2.3643
19	60	Biased-50k	600.22	598.26	-1.9604
20	60	Biased-50k	599.68	597.38	-2.2985
21	60	Biased-50k	599.92	598.95	-0.9705
24	100	Unbiased-100k	599.29	598.28	-1.017
25	100	Unbiased-100k	598.19	597.43	-0.7559
26	100	Unbiased-100k	600.08	598.87	-1.2053
27	100	Unbiased-100k	597.37	597.06	-0.305
28	100	Unbiased-100k	598.32	597.78	-0.5433
29	110	Biased-100k	598.8	595.63	-3.1718
30	110	Biased-100k	599.65	597.73	-1.9128
31	110	Biased-100k	598.59	595.38	-3.2114
32	110	Biased-100k	599.71	595.58	-4.1248
34	110	Biased-100k	598.23	595.08	-3.157

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.28	599.15	600.33	1.0566	598.36	599.3	600.59	1.1562	0.0812	0.14713	0.2637	0.10124
50	597.71	599.25	600.9	1.1298	596.4	598.25	600.18	1.3583	-1.3407	-0.99748	-0.6888	0.31392
60	599.01	599.69	600.22	0.44742	597.26	597.85	598.95	0.73288	-2.3643	-1.8404	-0.9705	0.57213
100	597.37	598.65	600.08	1.052	597.06	597.88	598.87	0.7118	-1.2053	-0.7653	-0.305	0.35993
110	598.23	599	599.71	0.65349	595.08	595.88	597.73	1.0587	-4.1248	-3.1156	-1.9128	0.78728

Device Test: 21.5 VREF_25C(REF|VREF/VREF4/3/3/0/0/90.9/634//1.8//25C/@VREF_25C)





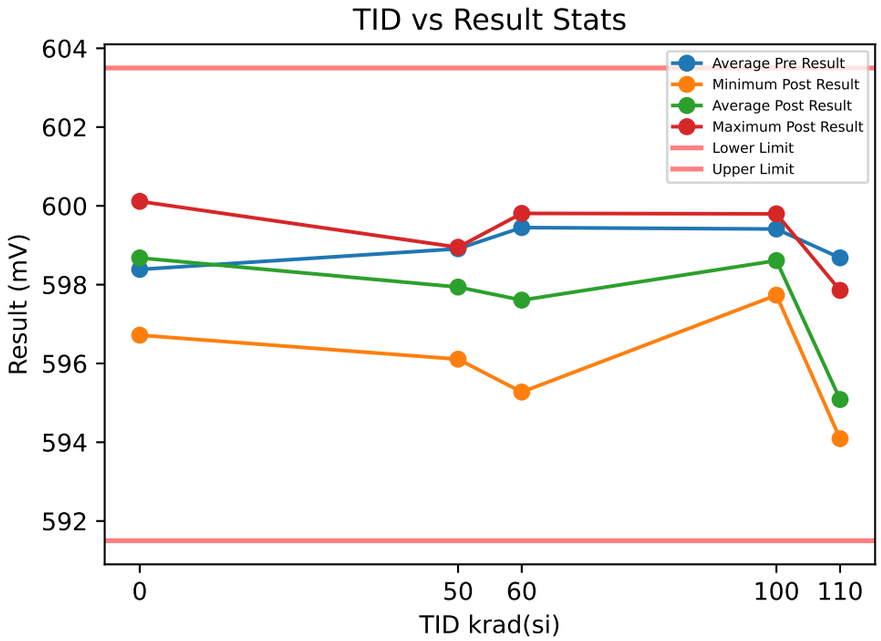
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

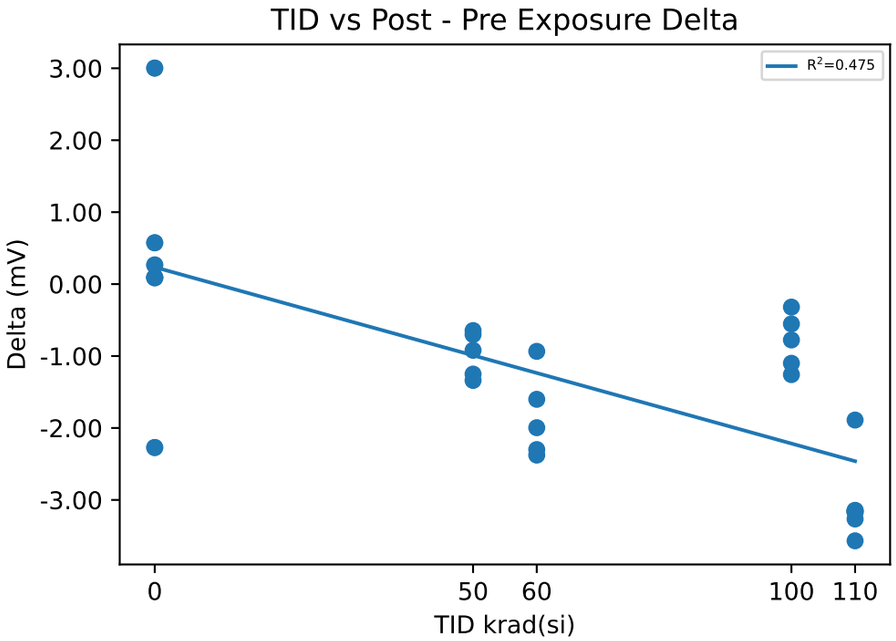
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.7	598.79	0.0962
2	0	CU2	598.26	598.34	0.0778
3	0	CU3	599.22	599.49	0.2648
11	50	Unbiased-50k	597.52	596.3	-1.2125
12	50	Unbiased-50k	599.75	598.43	-1.3248
13	50	Unbiased-50k	600.31	599.61	-0.7051
14	50	Unbiased-50k	598.69	598.03	-0.6642
16	50	Unbiased-50k	599.02	598.18	-0.844
17	60	Biased-50k	600.07	598.46	-1.6135
18	60	Biased-50k	599.47	597.11	-2.3611
19	60	Biased-50k	599.85	597.84	-2.0016
20	60	Biased-50k	599.46	597.15	-2.3032
21	60	Biased-50k	599.56	598.64	-0.9276
24	100	Unbiased-100k	598.55	597.55	-0.9998
25	100	Unbiased-100k	600.04	599.31	-0.7327
26	100	Unbiased-100k	599.43	598.2	-1.2376
27	100	Unbiased-100k	597.33	597.07	-0.2552
28	100	Unbiased-100k	598.5	597.88	-0.6186
29	110	Biased-100k	599.02	595.91	-3.1119
30	110	Biased-100k	599.24	597.36	-1.8816
31	110	Biased-100k	597.08	593.81	-3.2653
32	110	Biased-100k	600.77	595.79	-4.9843
34	110	Biased-100k	597.26	594.09	-3.1675

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.26	598.73	599.22	0.4788	598.34	598.87	599.49	0.57589	0.0778	0.14627	0.2648	0.10306
50	597.52	599.06	600.31	1.0694	596.3	598.11	599.61	1.1854	-1.3248	-0.95012	-0.6642	0.30095
60	599.46	599.68	600.07	0.26785	597.11	597.84	598.64	0.7108	-2.3611	-1.8414	-0.9276	0.59076
100	597.33	598.77	600.04	1.0323	597.07	598	599.31	0.84116	-1.2376	-0.76878	-0.2552	0.37443
110	597.08	598.67	600.77	1.5314	593.81	595.39	597.36	1.4547	-4.9843	-3.2821	-1.8816	1.1069

Device Test: 21.6 VREF(REF|VREF/VREF1/3/3/0/0/90.9/634//1.8//25C/@VREF)





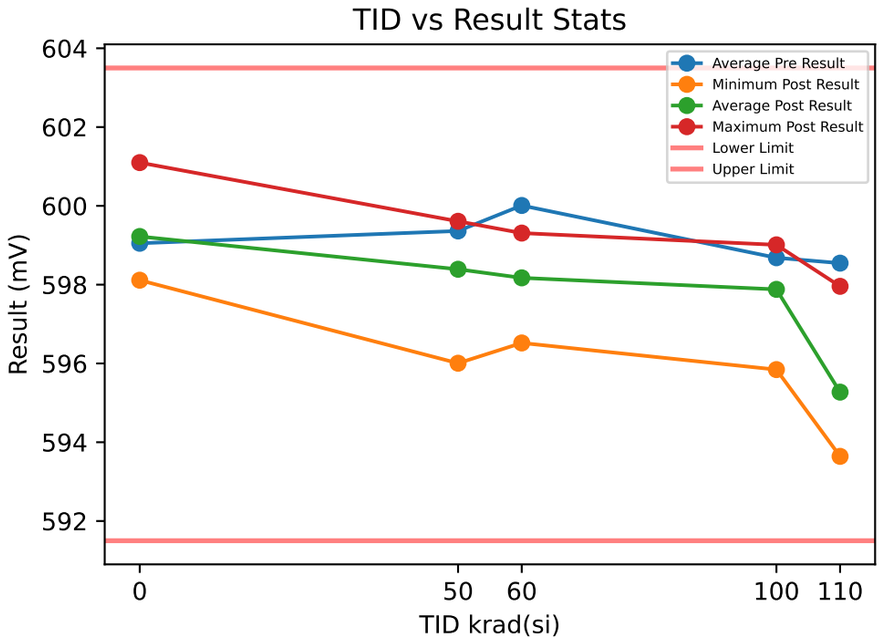
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

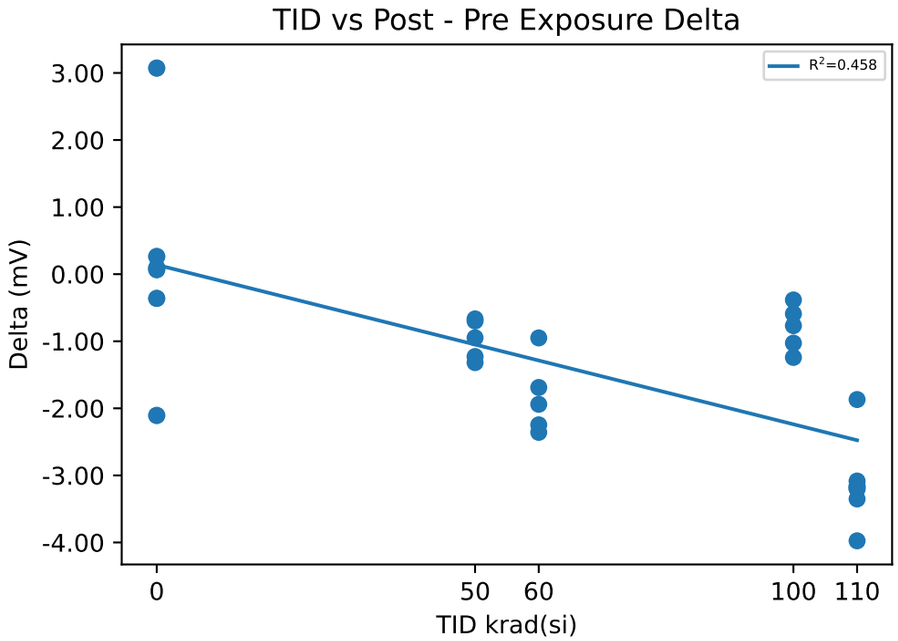
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.54	599.63	0.0941
2	0	CU2	596.63	596.72	0.0878
3	0	CU3	598.99	599.25	0.2661
11	50	Unbiased-50k	597.36	596.11	-1.2508
12	50	Unbiased-50k	600.29	598.95	-1.3392
13	50	Unbiased-50k	599.47	598.83	-0.6457
14	50	Unbiased-50k	598.72	598.02	-0.7015
16	50	Unbiased-50k	598.71	597.79	-0.9202
17	60	Biased-50k	599.76	598.16	-1.6014
18	60	Biased-50k	597.65	595.27	-2.3767
19	60	Biased-50k	599.5	597.5	-1.996
20	60	Biased-50k	599.59	597.29	-2.3001
21	60	Biased-50k	600.74	599.81	-0.9349
24	100	Unbiased-100k	598.83	597.73	-1.1007
25	100	Unbiased-100k	599.52	598.75	-0.7765
26	100	Unbiased-100k	601.06	599.8	-1.2579
27	100	Unbiased-100k	598.11	597.79	-0.3197
28	100	Unbiased-100k	599.54	598.98	-0.5534
29	110	Biased-100k	599.04	595.9	-3.1447
30	110	Biased-100k	599.74	597.85	-1.8897
31	110	Biased-100k	597.51	594.24	-3.2653
32	110	Biased-100k	599.85	596.28	-3.5684
34	110	Biased-100k	597.26	594.11	-3.1502

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.63	598.39	599.54	1.5447	596.72	598.54	599.63	1.5846	0.0878	0.14933	0.2661	0.10117
50	597.36	598.91	600.29	1.0836	596.11	597.94	598.95	1.1392	-1.3392	-0.97148	-0.6457	0.3142
60	597.65	599.45	600.74	1.1216	595.27	597.61	599.81	1.636	-2.3767	-1.8418	-0.9349	0.59165
100	598.11	599.41	601.06	1.0896	597.73	598.61	599.8	0.86651	-1.2579	-0.80164	-0.3197	0.38475
110	597.26	598.68	599.85	1.2264	594.11	595.68	597.85	1.5543	-3.5684	-3.0037	-1.8897	0.64608

Device Test: 21.7 VREF(REF|VREF/VREF2/3/3/0/0/90.9/634//1.8//25C/@VREF)





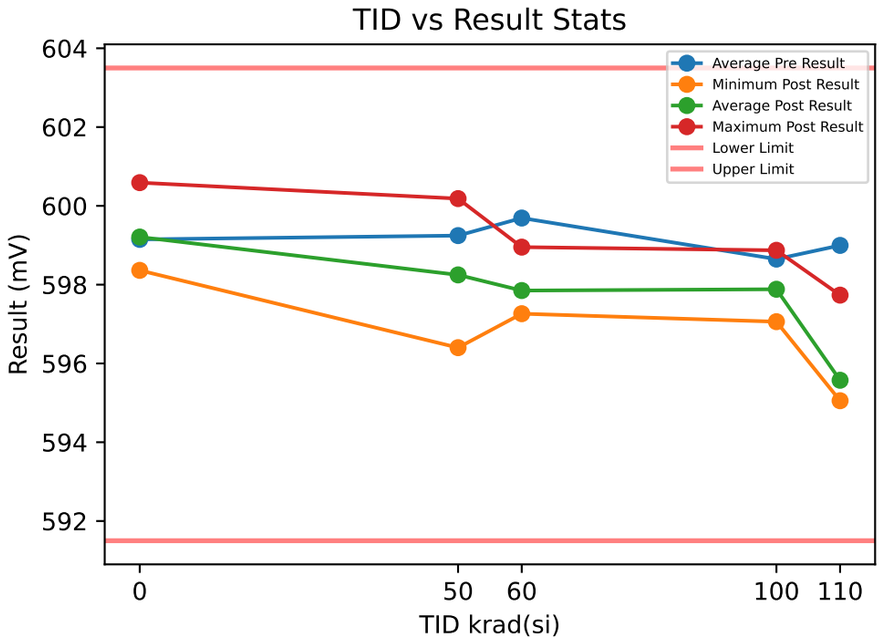
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

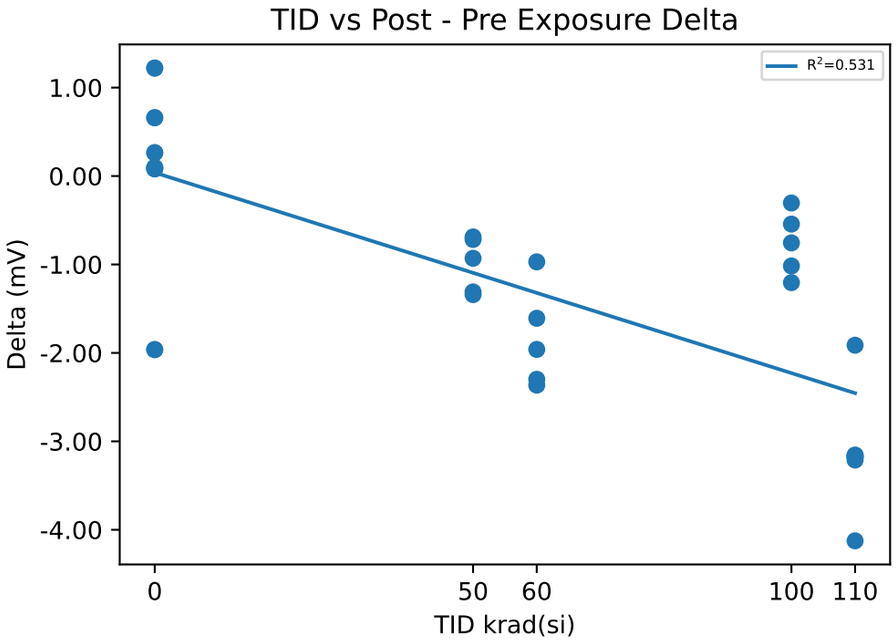
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.03	598.12	0.0961
2	0	CU2	598.47	598.54	0.0671
3	0	CU3	600.65	600.92	0.2633
11	50	Unbiased-50k	597.23	596.01	-1.2282
12	50	Unbiased-50k	599.6	598.29	-1.3185
13	50	Unbiased-50k	599.9	599.24	-0.6669
14	50	Unbiased-50k	599.51	598.82	-0.698
16	50	Unbiased-50k	600.56	599.61	-0.9482
17	60	Biased-50k	600.38	598.69	-1.6893
18	60	Biased-50k	598.88	596.52	-2.3582
19	60	Biased-50k	599.93	597.99	-1.9402
20	60	Biased-50k	600.6	598.36	-2.2462
21	60	Biased-50k	600.26	599.31	-0.9504
24	100	Unbiased-100k	598.85	597.82	-1.028
25	100	Unbiased-100k	599.78	599.01	-0.7675
26	100	Unbiased-100k	599.41	598.17	-1.2412
27	100	Unbiased-100k	596.23	595.84	-0.3843
28	100	Unbiased-100k	599.15	598.56	-0.5906
29	110	Biased-100k	598.49	595.41	-3.0839
30	110	Biased-100k	599.83	597.96	-1.8691
31	110	Biased-100k	596.99	593.64	-3.3516
32	110	Biased-100k	599.27	595.29	-3.9754
34	110	Biased-100k	598.15	594.99	-3.1643

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.03	599.05	600.65	1.405	598.12	599.19	600.92	1.5066	0.0671	0.14217	0.2633	0.1059
50	597.23	599.36	600.56	1.2583	596.01	598.39	599.61	1.4214	-1.3185	-0.97196	-0.6669	0.29767
60	598.88	600.01	600.6	0.67763	596.52	598.17	599.31	1.0433	-2.3582	-1.8369	-0.9504	0.56072
100	596.23	598.68	599.78	1.4141	595.84	597.88	599.01	1.2222	-1.2412	-0.80232	-0.3843	0.34071
110	596.99	598.55	599.83	1.0875	593.64	595.46	597.96	1.5653	-3.9754	-3.0889	-1.8691	0.76624

Device Test: 21.8 VREF(REF|VREF/VREF3/3/3/0/0/90.9/634//1.8//25C/@VREF)





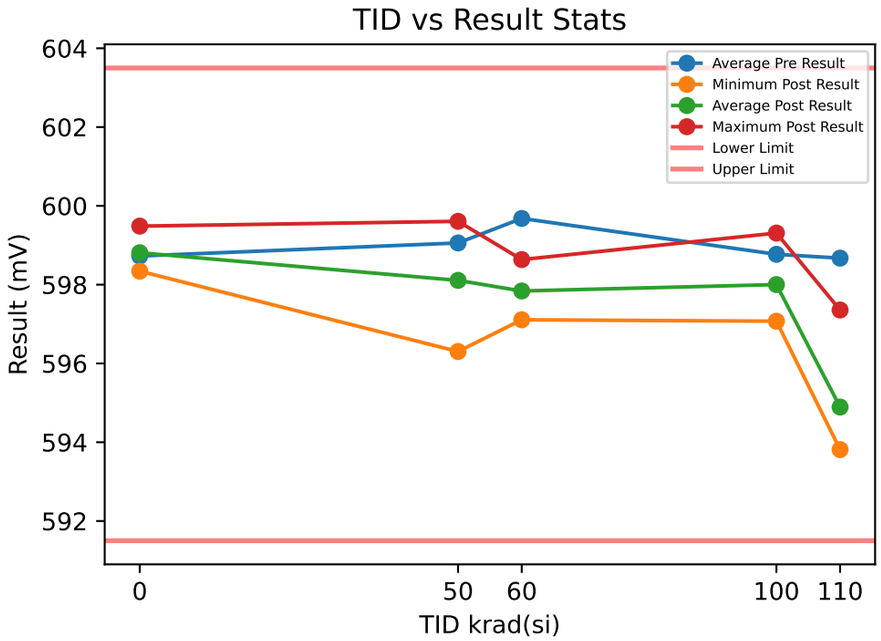
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

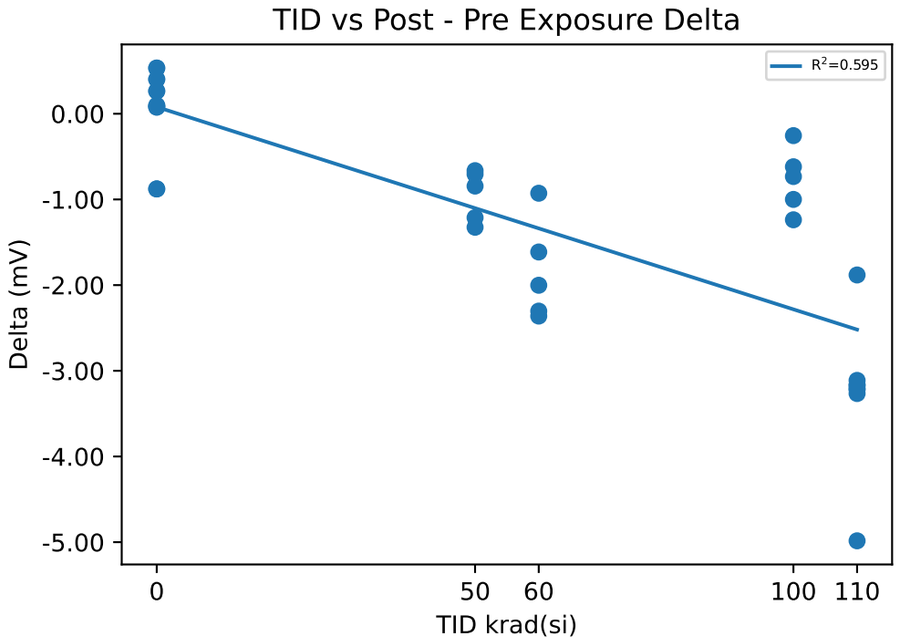
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.84	598.94	0.0965
2	0	CU2	598.28	598.36	0.0812
3	0	CU3	600.33	600.59	0.2637
11	50	Unbiased-50k	597.71	596.4	-1.3105
12	50	Unbiased-50k	599.23	597.89	-1.3407
13	50	Unbiased-50k	600.9	600.18	-0.7171
14	50	Unbiased-50k	599.23	598.54	-0.6888
16	50	Unbiased-50k	599.15	598.22	-0.9303
17	60	Biased-50k	599.01	597.4	-1.6083
18	60	Biased-50k	599.63	597.26	-2.3643
19	60	Biased-50k	600.22	598.26	-1.9604
20	60	Biased-50k	599.68	597.38	-2.2985
21	60	Biased-50k	599.92	598.95	-0.9705
24	100	Unbiased-100k	599.29	598.28	-1.017
25	100	Unbiased-100k	598.19	597.43	-0.7559
26	100	Unbiased-100k	600.08	598.87	-1.2053
27	100	Unbiased-100k	597.37	597.06	-0.305
28	100	Unbiased-100k	598.32	597.78	-0.5433
29	110	Biased-100k	598.8	595.63	-3.1718
30	110	Biased-100k	599.65	597.73	-1.9128
31	110	Biased-100k	598.59	595.38	-3.2114
32	110	Biased-100k	599.71	595.58	-4.1248
34	110	Biased-100k	598.23	595.08	-3.157

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.28	599.15	600.33	1.0566	598.36	599.3	600.59	1.1562	0.0812	0.14713	0.2637	0.10124
50	597.71	599.25	600.9	1.1298	596.4	598.25	600.18	1.3583	-1.3407	-0.99748	-0.6888	0.31392
60	599.01	599.69	600.22	0.44742	597.26	597.85	598.95	0.73288	-2.3643	-1.8404	-0.9705	0.57213
100	597.37	598.65	600.08	1.052	597.06	597.88	598.87	0.7118	-1.2053	-0.7653	-0.305	0.35993
110	598.23	599	599.71	0.65349	595.08	595.88	597.73	1.0587	-4.1248	-3.1156	-1.9128	0.78728

Device Test: 21.9 VREF(REF|VREF/VREF4/3/3/0/0/90.9/634//1.8//25C/@VREF)





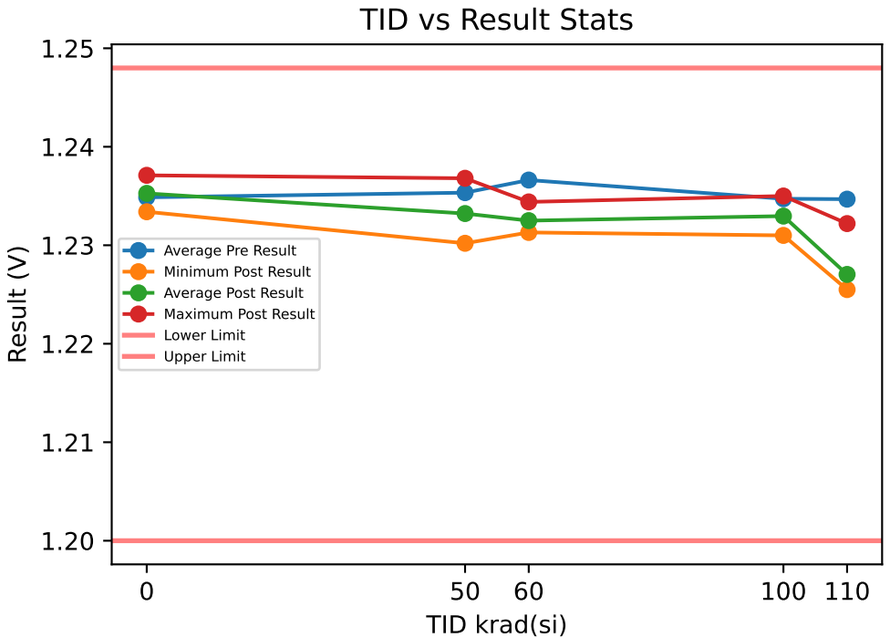
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

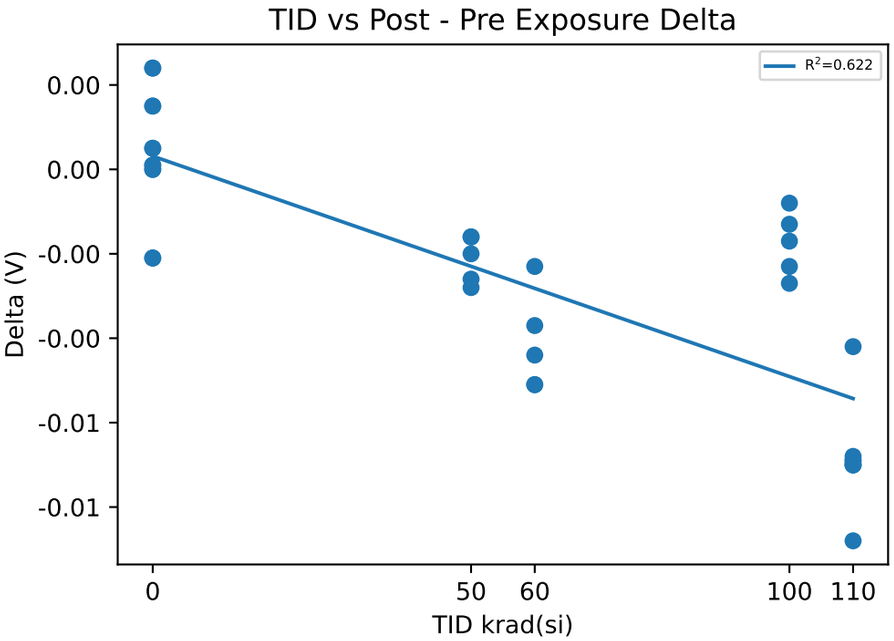
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.7	598.79	0.0962
2	0	CU2	598.26	598.34	0.0778
3	0	CU3	599.22	599.49	0.2648
11	50	Unbiased-50k	597.52	596.3	-1.2125
12	50	Unbiased-50k	599.75	598.43	-1.3248
13	50	Unbiased-50k	600.31	599.61	-0.7051
14	50	Unbiased-50k	598.69	598.03	-0.6642
16	50	Unbiased-50k	599.02	598.18	-0.844
17	60	Biased-50k	600.07	598.46	-1.6135
18	60	Biased-50k	599.47	597.11	-2.3611
19	60	Biased-50k	599.85	597.84	-2.0016
20	60	Biased-50k	599.46	597.15	-2.3032
21	60	Biased-50k	599.56	598.64	-0.9276
24	100	Unbiased-100k	598.55	597.55	-0.9998
25	100	Unbiased-100k	600.04	599.31	-0.7327
26	100	Unbiased-100k	599.43	598.2	-1.2376
27	100	Unbiased-100k	597.33	597.07	-0.2552
28	100	Unbiased-100k	598.5	597.88	-0.6186
29	110	Biased-100k	599.02	595.91	-3.1119
30	110	Biased-100k	599.24	597.36	-1.8816
31	110	Biased-100k	597.08	593.81	-3.2653
32	110	Biased-100k	600.77	595.79	-4.9843
34	110	Biased-100k	597.26	594.09	-3.1675

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.26	598.73	599.22	0.4788	598.34	598.87	599.49	0.57589	0.0778	0.14627	0.2648	0.10306
50	597.52	599.06	600.31	1.0694	596.3	598.11	599.61	1.1854	-1.3248	-0.95012	-0.6642	0.30095
60	599.46	599.68	600.07	0.26785	597.11	597.84	598.64	0.7108	-2.3611	-1.8414	-0.9276	0.59076
100	597.33	598.77	600.04	1.0323	597.07	598	599.31	0.84116	-1.2376	-0.76878	-0.2552	0.37443
110	597.08	598.67	600.77	1.5314	593.81	595.39	597.36	1.4547	-4.9843	-3.2821	-1.8816	1.1069

Device Test: 22.1 VREFCAP(REF|REFCAP/REFCAP/7/7/0/0/90.9/634//1.8//25C/@VREFCAP)





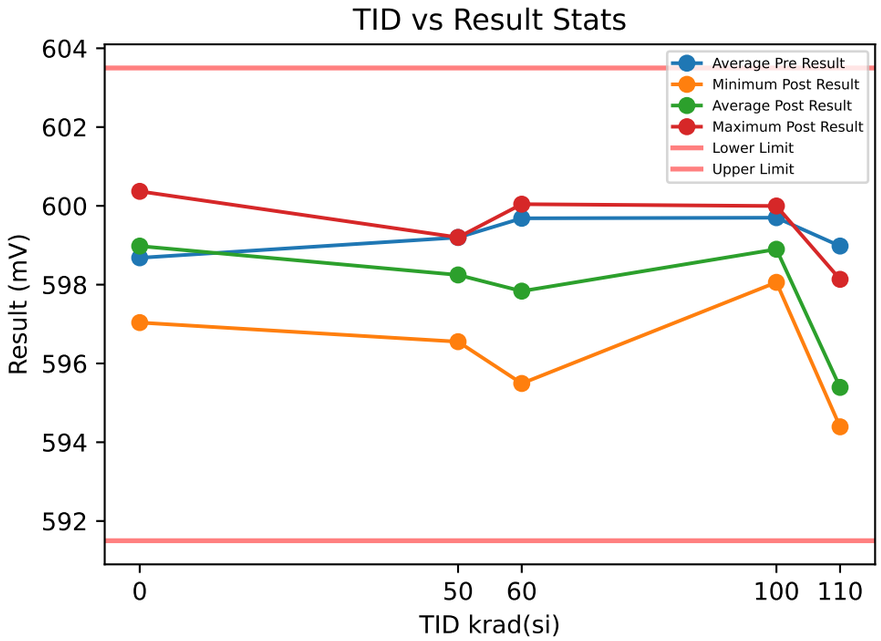
Test Results (Lower Limit = 1.2, Upper Limit = 1.248 (V))

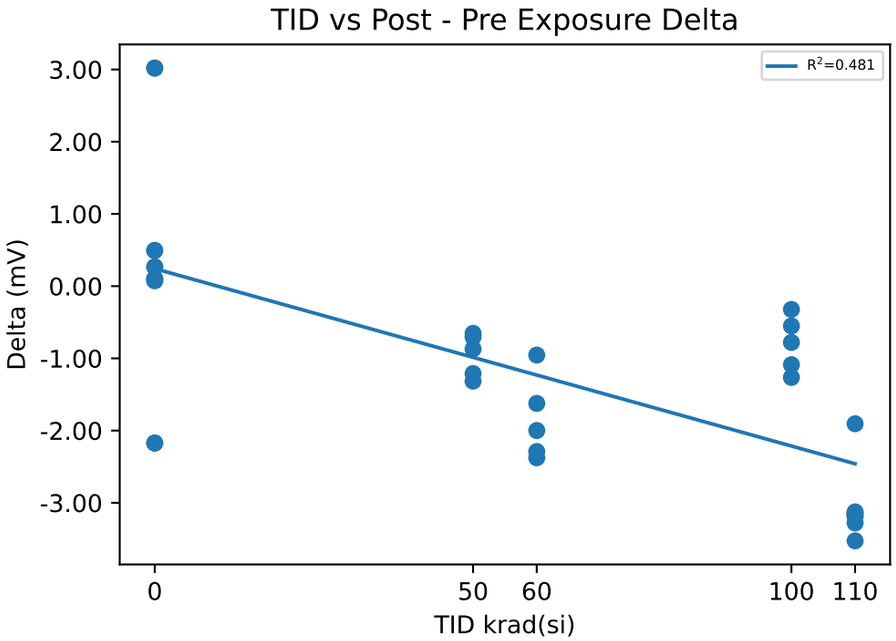
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.2356	1.2357	0.0001
2	0	CU2	1.2334	1.2334	0
3	0	CU3	1.2356	1.2361	0.0005
11	50	Unbiased-50k	1.2328	1.2302	-0.0026
12	50	Unbiased-50k	1.236	1.2332	-0.0028
13	50	Unbiased-50k	1.2384	1.2368	-0.0016
14	50	Unbiased-50k	1.2346	1.233	-0.0016
16	50	Unbiased-50k	1.2349	1.2329	-0.002
17	60	Biased-50k	1.237	1.2333	-0.0037
18	60	Biased-50k	1.2365	1.2314	-0.0051
19	60	Biased-50k	1.2357	1.2313	-0.0044
20	60	Biased-50k	1.2372	1.2321	-0.0051
21	60	Biased-50k	1.2367	1.2344	-0.0023
24	100	Unbiased-100k	1.2343	1.232	-0.0023
25	100	Unbiased-100k	1.2351	1.2334	-0.0017
26	100	Unbiased-100k	1.2377	1.235	-0.0027
27	100	Unbiased-100k	1.2318	1.231	-0.0008
28	100	Unbiased-100k	1.2347	1.2334	-0.0013
29	110	Biased-100k	1.2355	1.2287	-0.0068
30	110	Biased-100k	1.2364	1.2322	-0.0042
31	110	Biased-100k	1.2326	1.2256	-0.007
32	110	Biased-100k	1.2364	1.2276	-0.0088
34	110	Biased-100k	1.2325	1.2256	-0.0069

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2334	1.2349	1.2356	0.0012702	1.2334	1.2351	1.2361	0.0014572	0	0.0002	0.0005	0.00026458
50	1.2328	1.2353	1.2384	0.0020611	1.2302	1.2332	1.2368	0.0023499	-0.0028	-0.00212	-0.0016	0.00055857
60	1.2357	1.2366	1.2372	0.00058052	1.2313	1.2325	1.2344	0.0013285	-0.0051	-0.00412	-0.0023	0.0011713
100	1.2318	1.2347	1.2377	0.0021052	1.231	1.233	1.235	0.0015258	-0.0027	-0.00176	-0.0008	0.00076026
110	1.2325	1.2347	1.2364	0.0019791	1.2256	1.2279	1.2322	0.0027291	-0.0088	-0.00674	-0.0042	0.0016426

Device Test: 22.2 VREF_25C(REF|VREF/VREF1/7/7/0/0/90.9/634//1.8//25C/@VREF_25C)





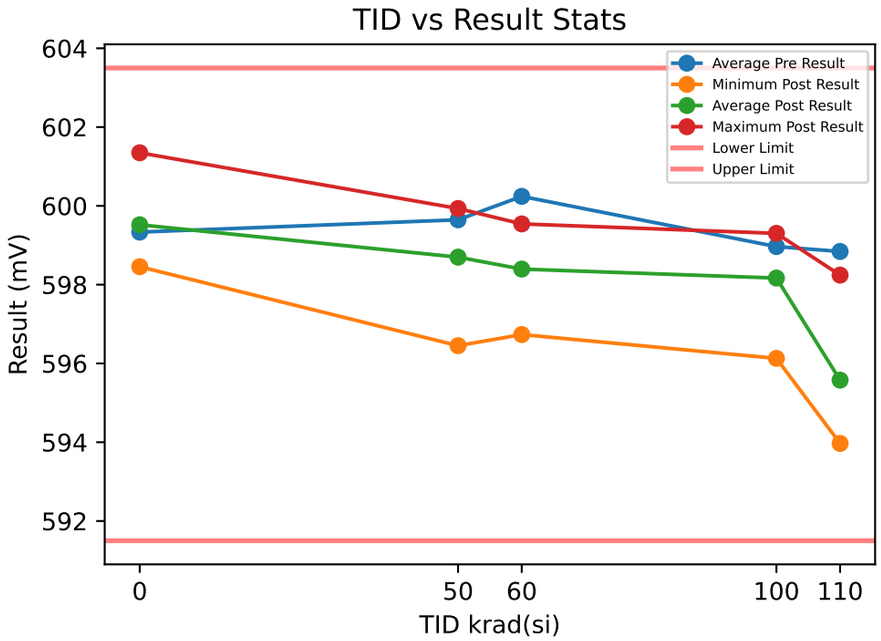
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

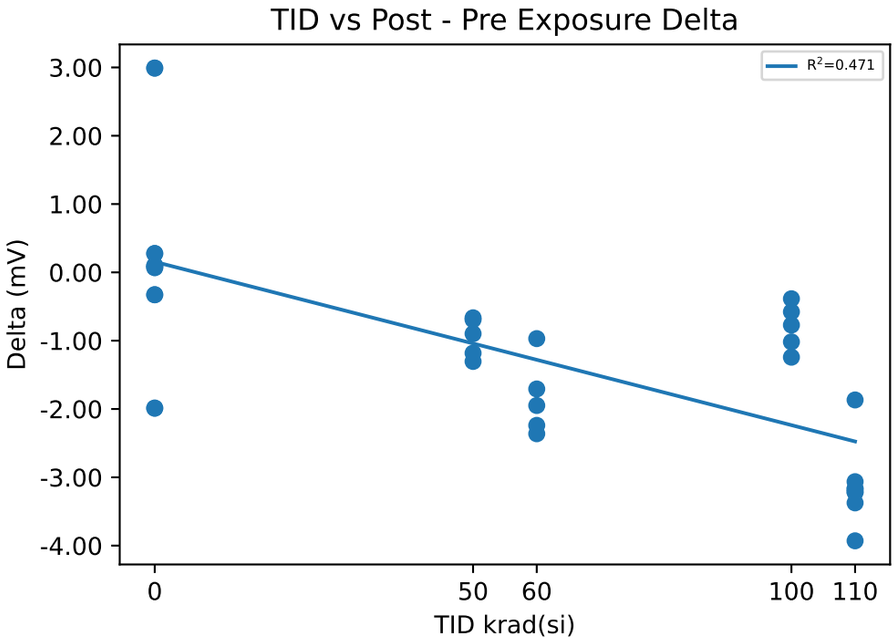
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.87	599.98	0.1023
2	0	CU2	596.96	597.04	0.077
3	0	CU3	599.21	599.48	0.2664
11	50	Unbiased-50k	597.76	596.55	-1.2104
12	50	Unbiased-50k	600.52	599.2	-1.3154
13	50	Unbiased-50k	599.74	599.08	-0.6539
14	50	Unbiased-50k	598.99	598.28	-0.7045
16	50	Unbiased-50k	598.98	598.11	-0.8699
17	60	Biased-50k	600.02	598.4	-1.6237
18	60	Biased-50k	597.87	595.49	-2.3768
19	60	Biased-50k	599.7	597.7	-1.9992
20	60	Biased-50k	599.83	597.54	-2.2901
21	60	Biased-50k	601	600.04	-0.9543
24	100	Unbiased-100k	599.15	598.06	-1.0874
25	100	Unbiased-100k	599.82	599.05	-0.7794
26	100	Unbiased-100k	601.26	600	-1.2642
27	100	Unbiased-100k	598.4	598.08	-0.3226
28	100	Unbiased-100k	599.87	599.32	-0.551
29	110	Biased-100k	599.36	596.24	-3.1262
30	110	Biased-100k	600.04	598.13	-1.9057
31	110	Biased-100k	597.86	594.58	-3.2793
32	110	Biased-100k	600.06	596.54	-3.5265
34	110	Biased-100k	597.58	594.43	-3.1422

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.96	598.68	599.87	1.5272	597.04	598.83	599.98	1.5726	0.077	0.14857	0.2664	0.10283
50	597.76	599.2	600.52	1.0219	596.55	598.25	599.2	1.0606	-1.3154	-0.95082	-0.6539	0.2982
60	597.87	599.68	601	1.1355	595.49	597.84	600.04	1.6424	-2.3768	-1.8488	-0.9543	0.58029
100	598.4	599.7	601.26	1.0586	598.06	598.9	600	0.83447	-1.2642	-0.80092	-0.3226	0.38354
110	597.58	598.98	600.06	1.1911	594.43	595.98	598.13	1.5309	-3.5265	-2.996	-1.9057	0.63023

Device Test: 22.3 VREF_25C(REF|VREF/VREF2/7/7/0/0/90.9/634//1.8//25C/@VREF_25C)





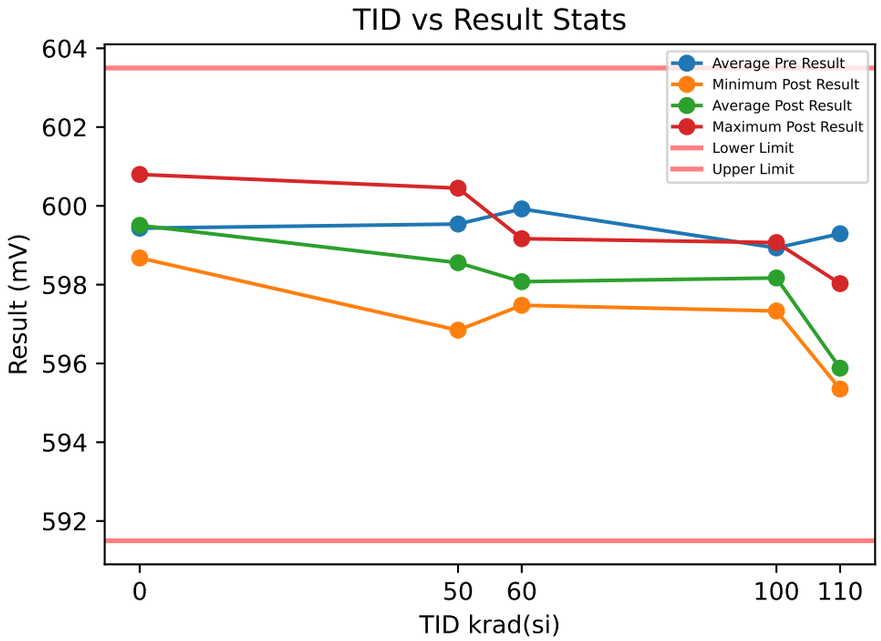
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

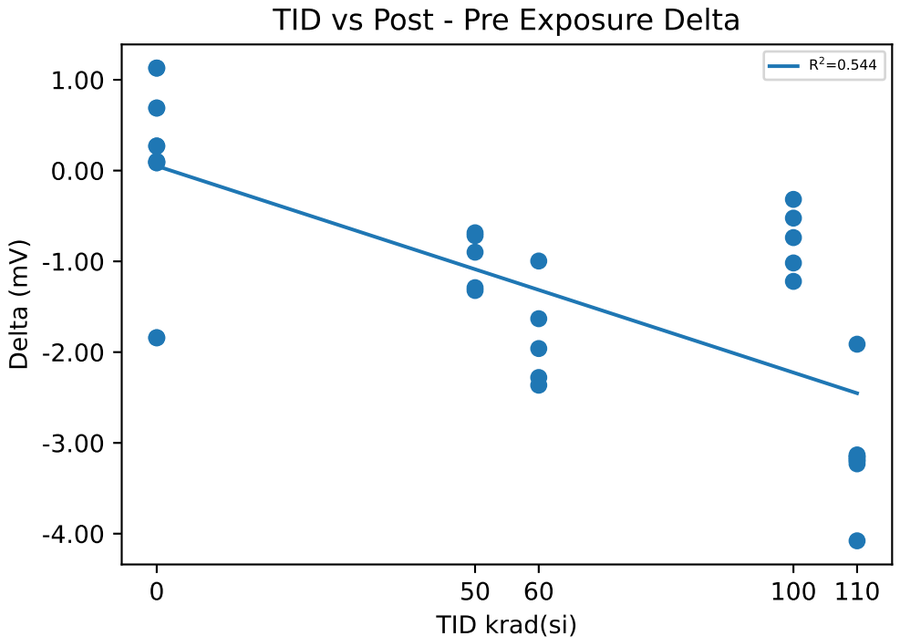
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.36	598.46	0.0983
2	0	CU2	598.79	598.86	0.0699
3	0	CU3	600.86	601.13	0.2756
11	50	Unbiased-50k	597.63	596.45	-1.1819
12	50	Unbiased-50k	599.84	598.53	-1.304
13	50	Unbiased-50k	600.16	599.49	-0.6651
14	50	Unbiased-50k	599.77	599.08	-0.6919
16	50	Unbiased-50k	600.83	599.93	-0.8979
17	60	Biased-50k	600.63	598.92	-1.707
18	60	Biased-50k	599.1	596.73	-2.3623
19	60	Biased-50k	600.14	598.19	-1.9489
20	60	Biased-50k	600.83	598.59	-2.2397
21	60	Biased-50k	600.51	599.54	-0.9699
24	100	Unbiased-100k	599.15	598.14	-1.0175
25	100	Unbiased-100k	600.07	599.3	-0.7711
26	100	Unbiased-100k	599.61	598.37	-1.2417
27	100	Unbiased-100k	596.51	596.13	-0.3861
28	100	Unbiased-100k	599.48	598.9	-0.5778
29	110	Biased-100k	598.8	595.74	-3.0642
30	110	Biased-100k	600.11	598.24	-1.8676
31	110	Biased-100k	597.34	593.97	-3.3743
32	110	Biased-100k	599.49	595.56	-3.9298
34	110	Biased-100k	598.47	595.3	-3.1678

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.36	599.33	600.86	1.3358	598.46	599.48	601.13	1.4429	0.0699	0.14793	0.2756	0.11147
50	597.63	599.65	600.83	1.2015	596.45	598.7	599.93	1.3584	-1.304	-0.94816	-0.6651	0.28704
60	599.1	600.24	600.83	0.68819	596.73	598.4	599.54	1.0533	-2.3623	-1.8456	-0.9699	0.55205
100	596.51	598.97	600.07	1.4098	596.13	598.17	599.3	1.2271	-1.2417	-0.79884	-0.3861	0.34056
110	597.34	598.84	600.11	1.0494	593.97	595.76	598.24	1.5507	-3.9298	-3.0807	-1.8676	0.75608

Device Test: 22.4 VREF_25C(REF|VREF/VREF3/7/7/0/0/90.9/634//1.8//25C/@VREF_25C)





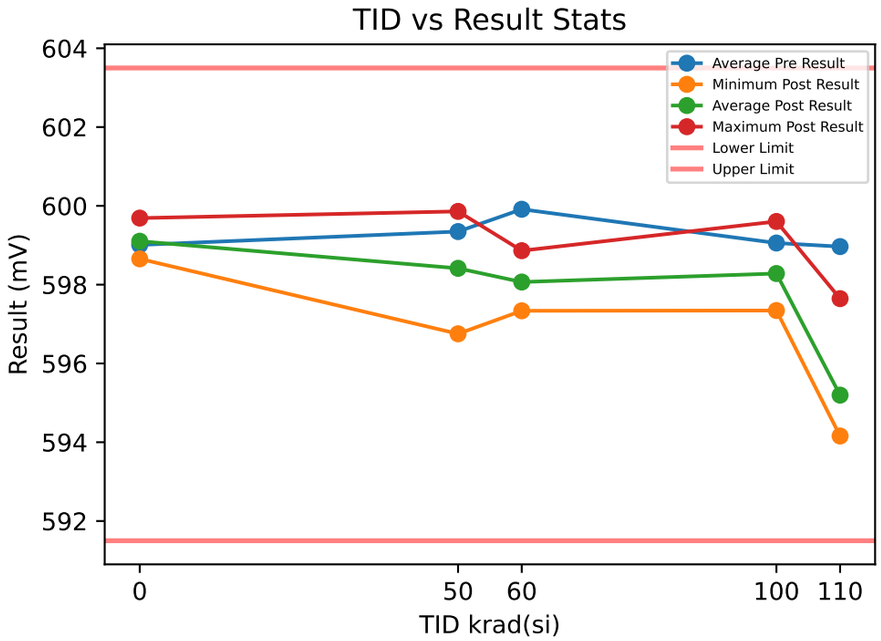
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

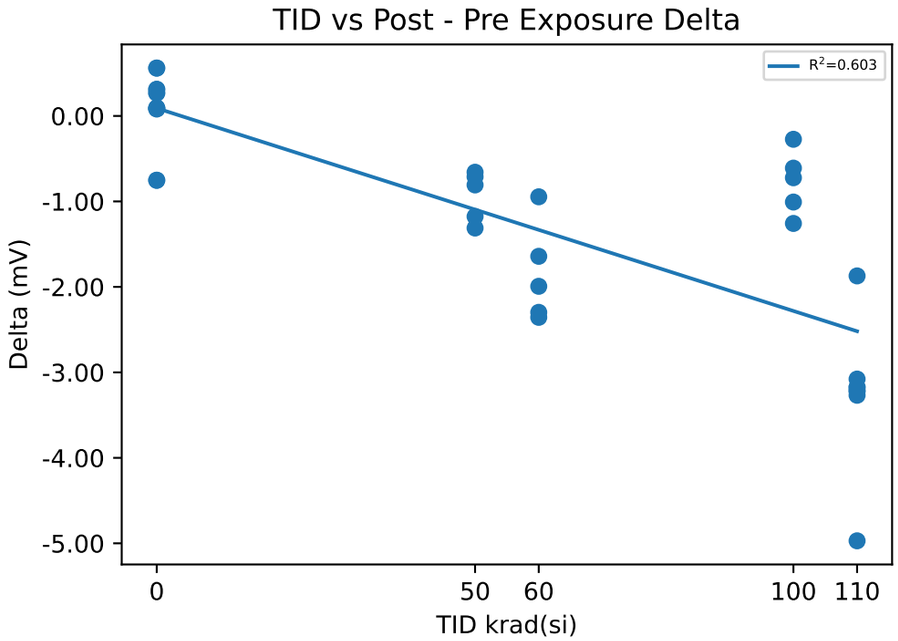
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.18	599.28	0.1004
2	0	CU2	598.59	598.68	0.0862
3	0	CU3	600.53	600.8	0.2703
11	50	Unbiased-50k	598.13	596.84	-1.2899
12	50	Unbiased-50k	599.46	598.13	-1.3209
13	50	Unbiased-50k	601.17	600.45	-0.7164
14	50	Unbiased-50k	599.49	598.81	-0.6853
16	50	Unbiased-50k	599.44	598.54	-0.899
17	60	Biased-50k	599.27	597.64	-1.6318
18	60	Biased-50k	599.84	597.48	-2.3642
19	60	Biased-50k	600.43	598.47	-1.9606
20	60	Biased-50k	599.91	597.63	-2.2797
21	60	Biased-50k	600.16	599.17	-0.9964
24	100	Unbiased-100k	599.61	598.59	-1.0177
25	100	Unbiased-100k	598.48	597.74	-0.7384
26	100	Unbiased-100k	600.29	599.07	-1.2206
27	100	Unbiased-100k	597.65	597.33	-0.3173
28	100	Unbiased-100k	598.64	598.12	-0.5237
29	110	Biased-100k	599.11	595.98	-3.1324
30	110	Biased-100k	599.94	598.03	-1.9127
31	110	Biased-100k	598.94	595.71	-3.2307
32	110	Biased-100k	599.93	595.85	-4.0787
34	110	Biased-100k	598.54	595.39	-3.1557

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.59	599.43	600.53	0.99235	598.68	599.59	600.8	1.0923	0.0862	0.1523	0.2703	0.10244
50	598.13	599.54	601.17	1.0769	596.84	598.56	600.45	1.2997	-1.3209	-0.9823	-0.6853	0.30623
60	599.27	599.92	600.43	0.43378	597.48	598.08	599.17	0.72422	-2.3642	-1.8465	-0.9964	0.55621
100	597.65	598.93	600.29	1.0292	597.33	598.17	599.07	0.68504	-1.2206	-0.76354	-0.3173	0.36428
110	598.54	599.29	599.94	0.62065	595.39	596.19	598.03	1.0495	-4.0787	-3.102	-1.9127	0.77278

Device Test: 22.5 VREF_25C(REF|VREF/VREF4/7/7/0/0/90.9/634//1.8//25C/@VREF_25C)





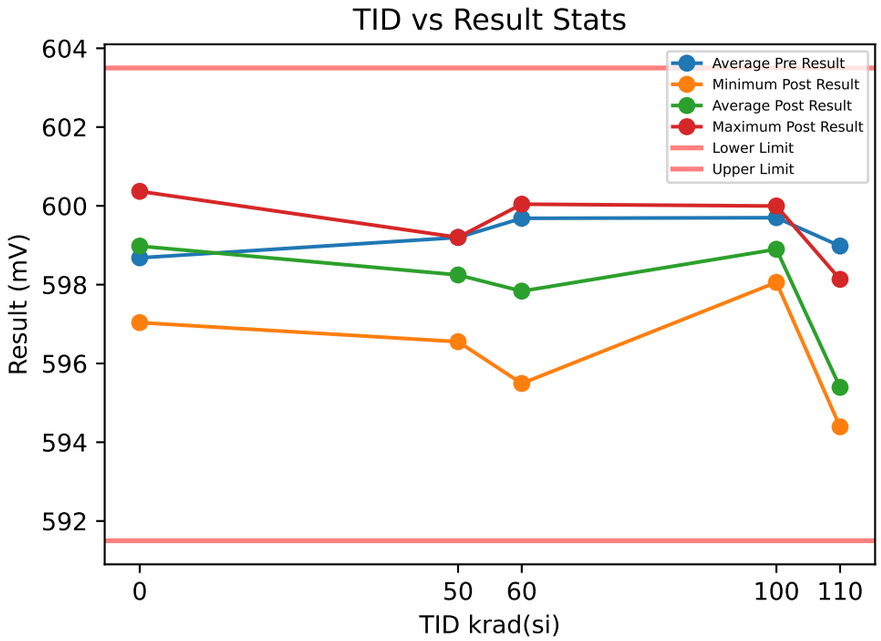
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

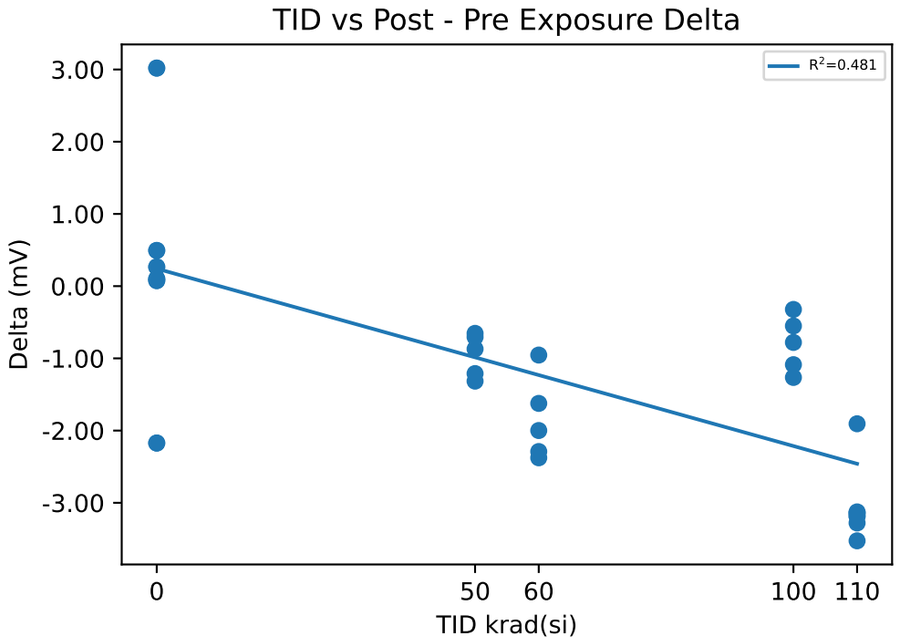
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.03	599.13	0.0938
2	0	CU2	598.57	598.65	0.0825
3	0	CU3	599.42	599.69	0.268
11	50	Unbiased-50k	597.93	596.75	-1.1766
12	50	Unbiased-50k	599.98	598.67	-1.3114
13	50	Unbiased-50k	600.57	599.86	-0.7118
14	50	Unbiased-50k	598.95	598.29	-0.6585
16	50	Unbiased-50k	599.31	598.5	-0.8073
17	60	Biased-50k	600.33	598.69	-1.6423
18	60	Biased-50k	599.69	597.34	-2.3562
19	60	Biased-50k	600.06	598.06	-1.9931
20	60	Biased-50k	599.68	597.39	-2.2978
21	60	Biased-50k	599.81	598.86	-0.946
24	100	Unbiased-100k	598.87	597.86	-1.0073
25	100	Unbiased-100k	600.33	599.6	-0.7232
26	100	Unbiased-100k	599.64	598.38	-1.2577
27	100	Unbiased-100k	597.62	597.34	-0.2731
28	100	Unbiased-100k	598.83	598.22	-0.6105
29	110	Biased-100k	599.32	596.24	-3.0783
30	110	Biased-100k	599.52	597.64	-1.8715
31	110	Biased-100k	597.43	594.16	-3.2679
32	110	Biased-100k	601	596.03	-4.9708
34	110	Biased-100k	597.57	594.39	-3.1735

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.57	599.01	599.42	0.4252	598.65	599.16	599.69	0.51813	0.0825	0.1481	0.268	0.10399
50	597.93	599.35	600.57	1.0095	596.75	598.41	599.86	1.1113	-1.3114	-0.93312	-0.6585	0.29266
60	599.68	599.91	600.33	0.2756	597.34	598.07	598.86	0.709	-2.3562	-1.8471	-0.946	0.57826
100	597.62	599.06	600.33	1.0148	597.34	598.28	599.6	0.8396	-1.2577	-0.77436	-0.2731	0.37703
110	597.43	598.97	601	1.4922	594.16	595.69	597.64	1.4376	-4.9708	-3.2724	-1.8715	1.1062

Device Test: 22.6 VREF(REF|VREF/VREF1/7/7/0/0/90.9/634//1.8//25C/@VREF)





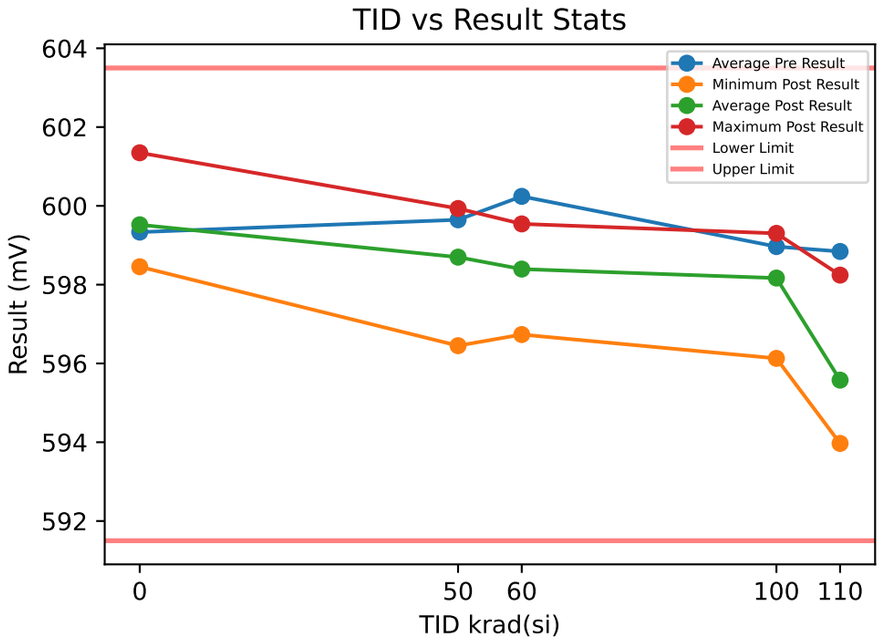
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

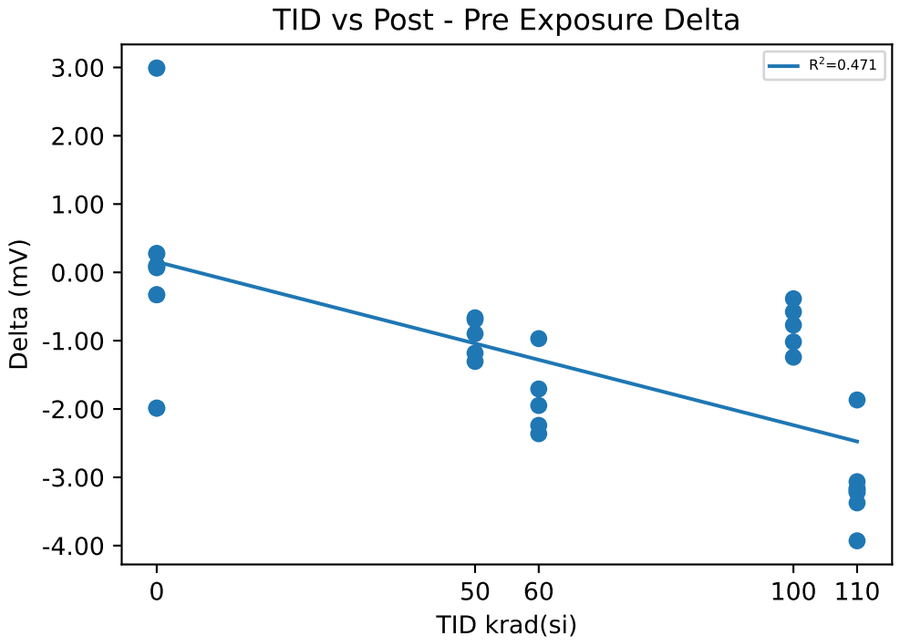
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.87	599.98	0.1023
2	0	CU2	596.96	597.04	0.077
3	0	CU3	599.21	599.48	0.2664
11	50	Unbiased-50k	597.76	596.55	-1.2104
12	50	Unbiased-50k	600.52	599.2	-1.3154
13	50	Unbiased-50k	599.74	599.08	-0.6539
14	50	Unbiased-50k	598.99	598.28	-0.7045
16	50	Unbiased-50k	598.98	598.11	-0.8699
17	60	Biased-50k	600.02	598.4	-1.6237
18	60	Biased-50k	597.87	595.49	-2.3768
19	60	Biased-50k	599.7	597.7	-1.9992
20	60	Biased-50k	599.83	597.54	-2.2901
21	60	Biased-50k	601	600.04	-0.9543
24	100	Unbiased-100k	599.15	598.06	-1.0874
25	100	Unbiased-100k	599.82	599.05	-0.7794
26	100	Unbiased-100k	601.26	600	-1.2642
27	100	Unbiased-100k	598.4	598.08	-0.3226
28	100	Unbiased-100k	599.87	599.32	-0.551
29	110	Biased-100k	599.36	596.24	-3.1262
30	110	Biased-100k	600.04	598.13	-1.9057
31	110	Biased-100k	597.86	594.58	-3.2793
32	110	Biased-100k	600.06	596.54	-3.5265
34	110	Biased-100k	597.58	594.43	-3.1422

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	596.96	598.68	599.87	1.5272	597.04	598.83	599.98	1.5726	0.077	0.14857	0.2664	0.10283
50	597.76	599.2	600.52	1.0219	596.55	598.25	599.2	1.0606	-1.3154	-0.95082	-0.6539	0.2982
60	597.87	599.68	601	1.1355	595.49	597.84	600.04	1.6424	-2.3768	-1.8488	-0.9543	0.58029
100	598.4	599.7	601.26	1.0586	598.06	598.9	600	0.83447	-1.2642	-0.80092	-0.3226	0.38354
110	597.58	598.98	600.06	1.1911	594.43	595.98	598.13	1.5309	-3.5265	-2.996	-1.9057	0.63023

Device Test: 22.7 VREF(REF|VREF/VREF2/7/7/0/0/90.9/634//1.8//25C/@VREF)





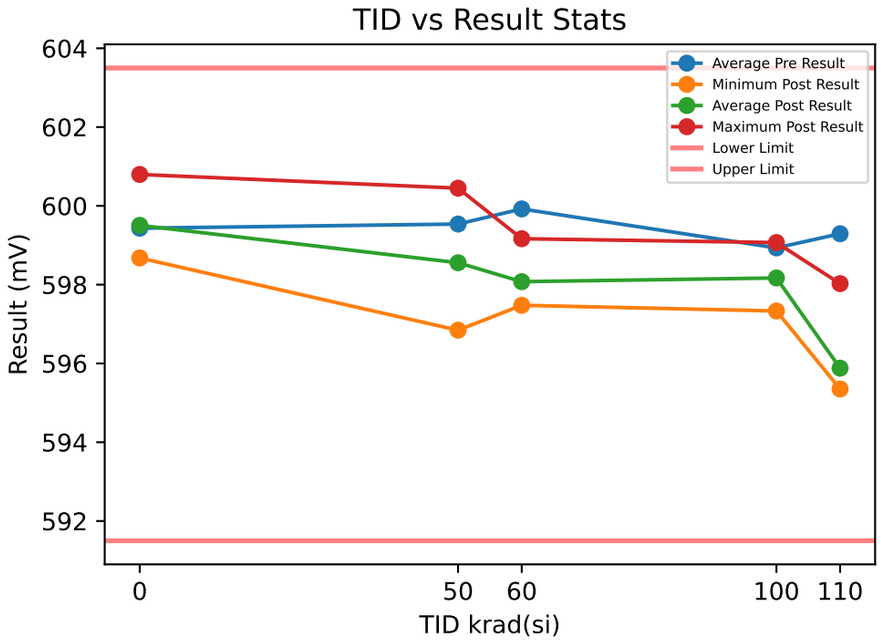
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

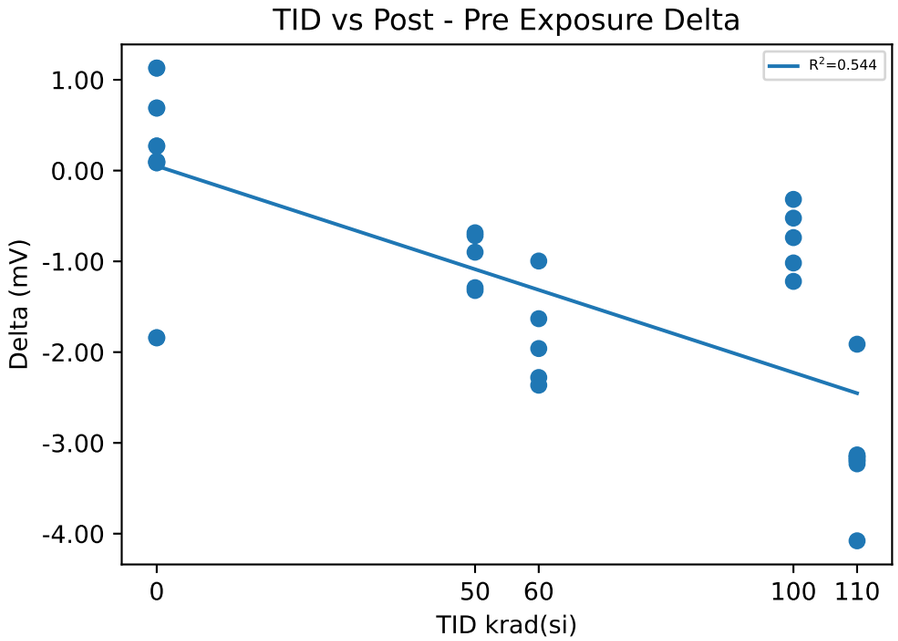
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	598.36	598.46	0.0983
2	0	CU2	598.79	598.86	0.0699
3	0	CU3	600.86	601.13	0.2756
11	50	Unbiased-50k	597.63	596.45	-1.1819
12	50	Unbiased-50k	599.84	598.53	-1.304
13	50	Unbiased-50k	600.16	599.49	-0.6651
14	50	Unbiased-50k	599.77	599.08	-0.6919
16	50	Unbiased-50k	600.83	599.93	-0.8979
17	60	Biased-50k	600.63	598.92	-1.707
18	60	Biased-50k	599.1	596.73	-2.3623
19	60	Biased-50k	600.14	598.19	-1.9489
20	60	Biased-50k	600.83	598.59	-2.2397
21	60	Biased-50k	600.51	599.54	-0.9699
24	100	Unbiased-100k	599.15	598.14	-1.0175
25	100	Unbiased-100k	600.07	599.3	-0.7711
26	100	Unbiased-100k	599.61	598.37	-1.2417
27	100	Unbiased-100k	596.51	596.13	-0.3861
28	100	Unbiased-100k	599.48	598.9	-0.5778
29	110	Biased-100k	598.8	595.74	-3.0642
30	110	Biased-100k	600.11	598.24	-1.8676
31	110	Biased-100k	597.34	593.97	-3.3743
32	110	Biased-100k	599.49	595.56	-3.9298
34	110	Biased-100k	598.47	595.3	-3.1678

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.36	599.33	600.86	1.3358	598.46	599.48	601.13	1.4429	0.0699	0.14793	0.2756	0.11147
50	597.63	599.65	600.83	1.2015	596.45	598.7	599.93	1.3584	-1.304	-0.94816	-0.6651	0.28704
60	599.1	600.24	600.83	0.68819	596.73	598.4	599.54	1.0533	-2.3623	-1.8456	-0.9699	0.55205
100	596.51	598.97	600.07	1.4098	596.13	598.17	599.3	1.2271	-1.2417	-0.79884	-0.3861	0.34056
110	597.34	598.84	600.11	1.0494	593.97	595.76	598.24	1.5507	-3.9298	-3.0807	-1.8676	0.75608

Device Test: 22.8 VREF(REF|VREF/VREF3/7/7/0/0/90.9/634//1.8//25C/@VREF)





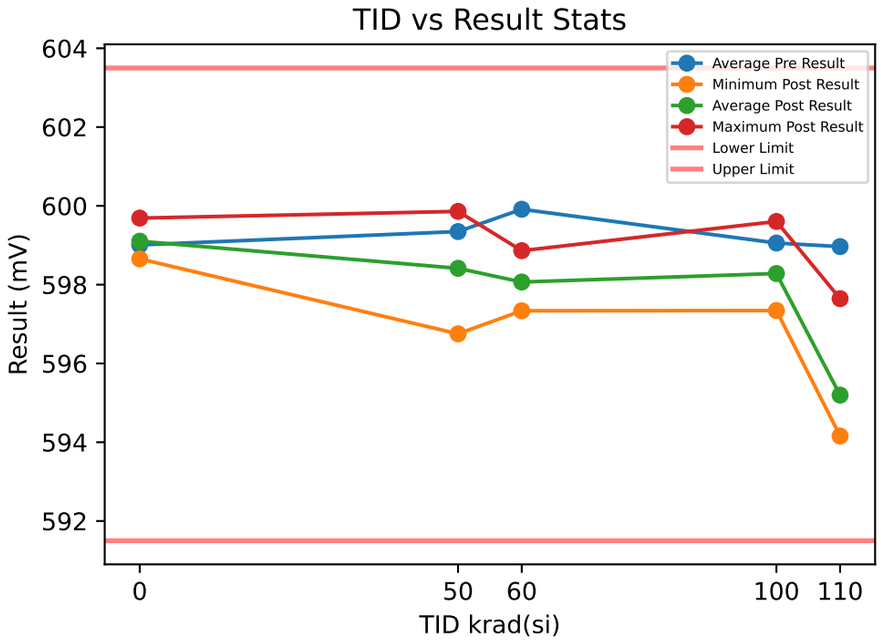
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

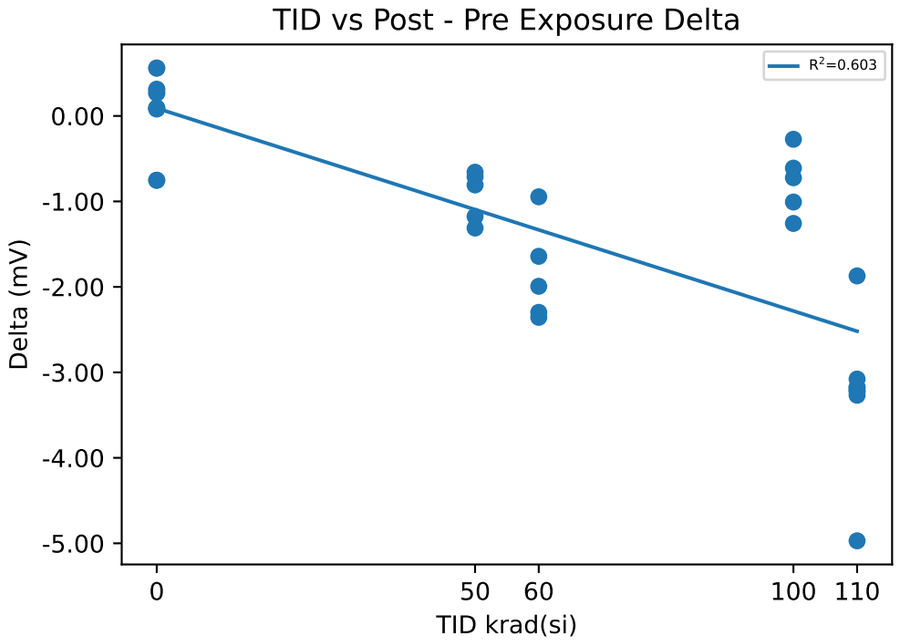
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.18	599.28	0.1004
2	0	CU2	598.59	598.68	0.0862
3	0	CU3	600.53	600.8	0.2703
11	50	Unbiased-50k	598.13	596.84	-1.2899
12	50	Unbiased-50k	599.46	598.13	-1.3209
13	50	Unbiased-50k	601.17	600.45	-0.7164
14	50	Unbiased-50k	599.49	598.81	-0.6853
16	50	Unbiased-50k	599.44	598.54	-0.899
17	60	Biased-50k	599.27	597.64	-1.6318
18	60	Biased-50k	599.84	597.48	-2.3642
19	60	Biased-50k	600.43	598.47	-1.9606
20	60	Biased-50k	599.91	597.63	-2.2797
21	60	Biased-50k	600.16	599.17	-0.9964
24	100	Unbiased-100k	599.61	598.59	-1.0177
25	100	Unbiased-100k	598.48	597.74	-0.7384
26	100	Unbiased-100k	600.29	599.07	-1.2206
27	100	Unbiased-100k	597.65	597.33	-0.3173
28	100	Unbiased-100k	598.64	598.12	-0.5237
29	110	Biased-100k	599.11	595.98	-3.1324
30	110	Biased-100k	599.94	598.03	-1.9127
31	110	Biased-100k	598.94	595.71	-3.2307
32	110	Biased-100k	599.93	595.85	-4.0787
34	110	Biased-100k	598.54	595.39	-3.1557

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.59	599.43	600.53	0.99235	598.68	599.59	600.8	1.0923	0.0862	0.1523	0.2703	0.10244
50	598.13	599.54	601.17	1.0769	596.84	598.56	600.45	1.2997	-1.3209	-0.9823	-0.6853	0.30623
60	599.27	599.92	600.43	0.43378	597.48	598.08	599.17	0.72422	-2.3642	-1.8465	-0.9964	0.55621
100	597.65	598.93	600.29	1.0292	597.33	598.17	599.07	0.68504	-1.2206	-0.76354	-0.3173	0.36428
110	598.54	599.29	599.94	0.62065	595.39	596.19	598.03	1.0495	-4.0787	-3.102	-1.9127	0.77278

Device Test: 22.9 VREF(REF|VREF/VREF4/7/7/0/0/90.9/634//1.8//25C/@VREF)





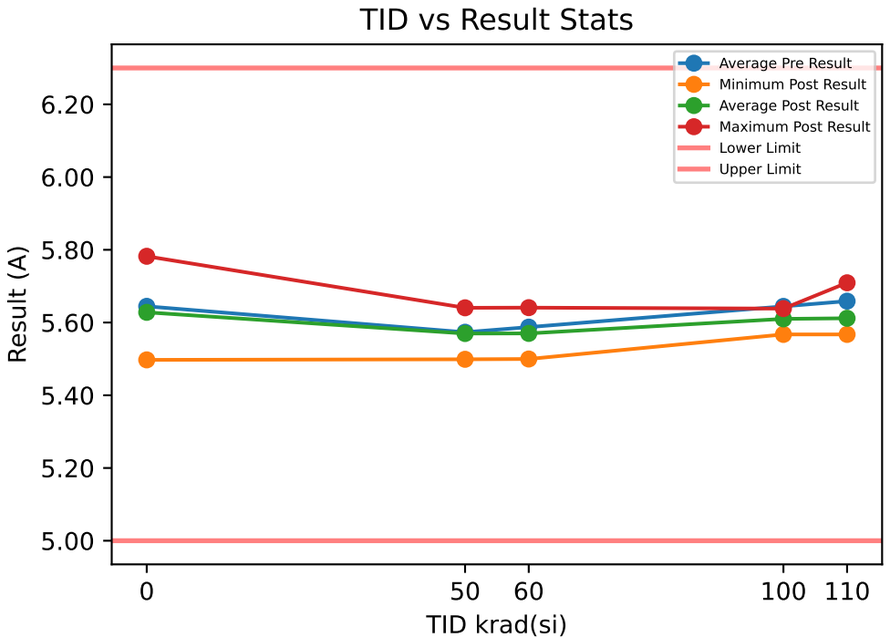
Test Results (Lower Limit = 591.5, Upper Limit = 603.5 (mV))

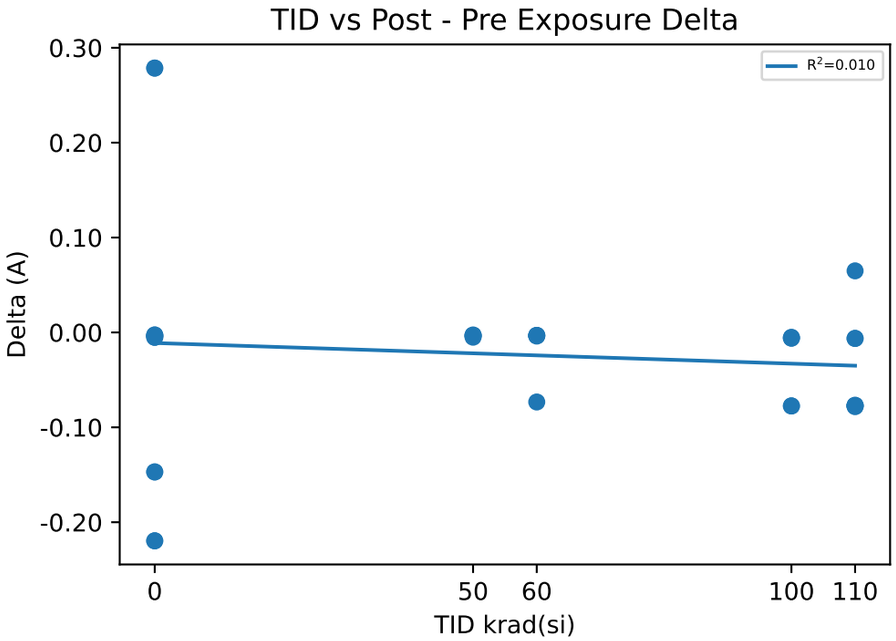
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	599.03	599.13	0.0938
2	0	CU2	598.57	598.65	0.0825
3	0	CU3	599.42	599.69	0.268
11	50	Unbiased-50k	597.93	596.75	-1.1766
12	50	Unbiased-50k	599.98	598.67	-1.3114
13	50	Unbiased-50k	600.57	599.86	-0.7118
14	50	Unbiased-50k	598.95	598.29	-0.6585
16	50	Unbiased-50k	599.31	598.5	-0.8073
17	60	Biased-50k	600.33	598.69	-1.6423
18	60	Biased-50k	599.69	597.34	-2.3562
19	60	Biased-50k	600.06	598.06	-1.9931
20	60	Biased-50k	599.68	597.39	-2.2978
21	60	Biased-50k	599.81	598.86	-0.946
24	100	Unbiased-100k	598.87	597.86	-1.0073
25	100	Unbiased-100k	600.33	599.6	-0.7232
26	100	Unbiased-100k	599.64	598.38	-1.2577
27	100	Unbiased-100k	597.62	597.34	-0.2731
28	100	Unbiased-100k	598.83	598.22	-0.6105
29	110	Biased-100k	599.32	596.24	-3.0783
30	110	Biased-100k	599.52	597.64	-1.8715
31	110	Biased-100k	597.43	594.16	-3.2679
32	110	Biased-100k	601	596.03	-4.9708
34	110	Biased-100k	597.57	594.39	-3.1735

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	598.57	599.01	599.42	0.4252	598.65	599.16	599.69	0.51813	0.0825	0.1481	0.268	0.10399
50	597.93	599.35	600.57	1.0095	596.75	598.41	599.86	1.1113	-1.3114	-0.93312	-0.6585	0.29266
60	599.68	599.91	600.33	0.2756	597.34	598.07	598.86	0.709	-2.3562	-1.8471	-0.946	0.57826
100	597.62	599.06	600.33	1.0148	597.34	598.28	599.6	0.8396	-1.2577	-0.77436	-0.2731	0.37703
110	597.43	598.97	601	1.4922	594.16	595.69	597.64	1.4376	-4.9708	-3.2724	-1.8715	1.1062

Device Test: 26.2 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW1/3/3///90.9/634//1.8///@HIGH_SIDE_OC)





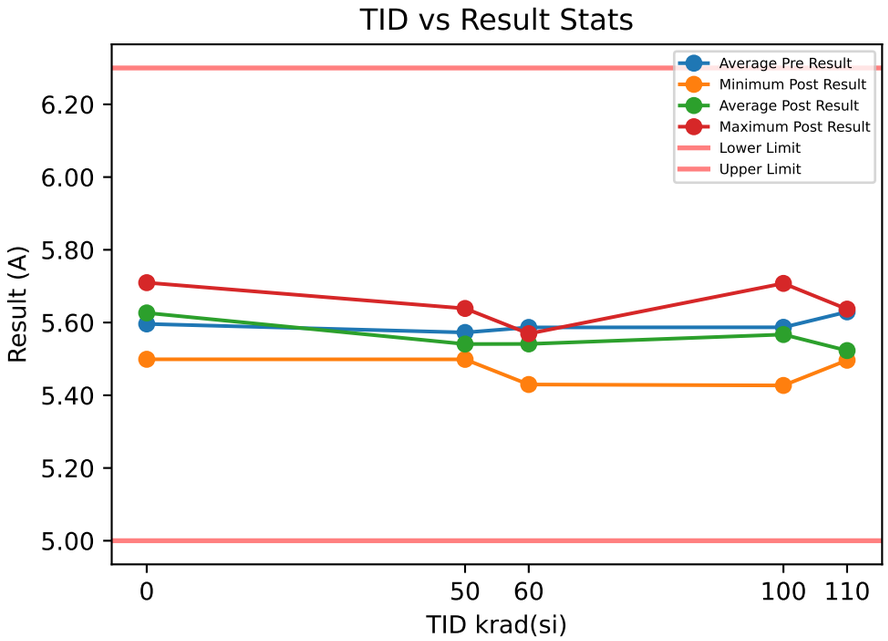
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

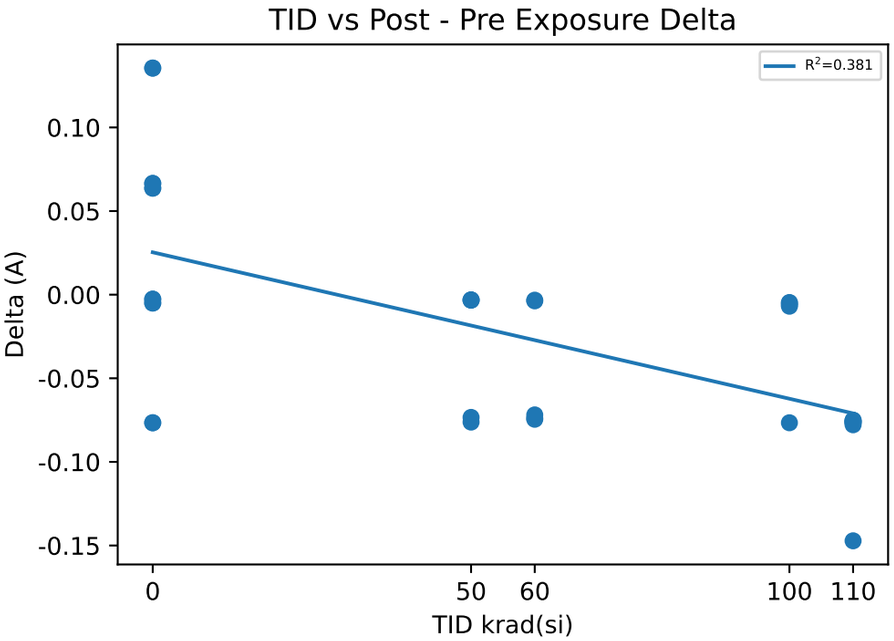
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7873	5.7822	-0.0051
2	0	CU2	5.5021	5.4994	-0.0027
3	0	CU3	5.6443	5.6408	-0.0035
11	50	Unbiased-50k	5.5732	5.5702	-0.003
12	50	Unbiased-50k	5.5021	5.4989	-0.0032
13	50	Unbiased-50k	5.6446	5.6396	-0.005
14	50	Unbiased-50k	5.6443	5.6405	-0.0038
16	50	Unbiased-50k	5.5024	5.4997	-0.0027
17	60	Biased-50k	5.573	5.4997	-0.0733
18	60	Biased-50k	5.5731	5.5699	-0.0032
19	60	Biased-50k	5.5731	5.5699	-0.0032
20	60	Biased-50k	5.6447	5.6409	-0.0038
21	60	Biased-50k	5.5731	5.57	-0.0031
24	100	Unbiased-100k	5.5731	5.568	-0.0051
25	100	Unbiased-100k	5.7158	5.6383	-0.0775
26	100	Unbiased-100k	5.5731	5.5673	-0.0058
27	100	Unbiased-100k	5.7157	5.6383	-0.0774
28	100	Unbiased-100k	5.6443	5.6382	-0.0061
29	110	Biased-100k	5.6444	5.5677	-0.0767
30	110	Biased-100k	5.7875	5.7093	-0.0782
31	110	Biased-100k	5.6444	5.5674	-0.077
32	110	Biased-100k	5.5731	5.638	0.0649
34	110	Biased-100k	5.6446	5.5673	-0.0773

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5021	5.6446	5.7873	0.1426	5.4994	5.6408	5.7822	0.1414	-0.0051	-0.0037667	-0.0027	0.001222
50	5.5021	5.5733	5.6446	0.0711	5.4989	5.5698	5.6405	0.070377	-0.005	-0.00354	-0.0027	0.00090995
60	5.573	5.5874	5.6447	0.032032	5.4997	5.5701	5.6409	0.049922	-0.0733	-0.01732	-0.0031	0.031295
100	5.5731	5.6444	5.7158	0.071325	5.5673	5.61	5.6383	0.038679	-0.0775	-0.03438	-0.0051	0.039319
110	5.5731	5.6588	5.7875	0.078302	5.5673	5.6099	5.7093	0.063387	-0.0782	-0.04886	0.0649	0.063596

Device Test: 26.3 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW2/3/3///90.9/634//1.8///@HIGH_SIDE_OC)





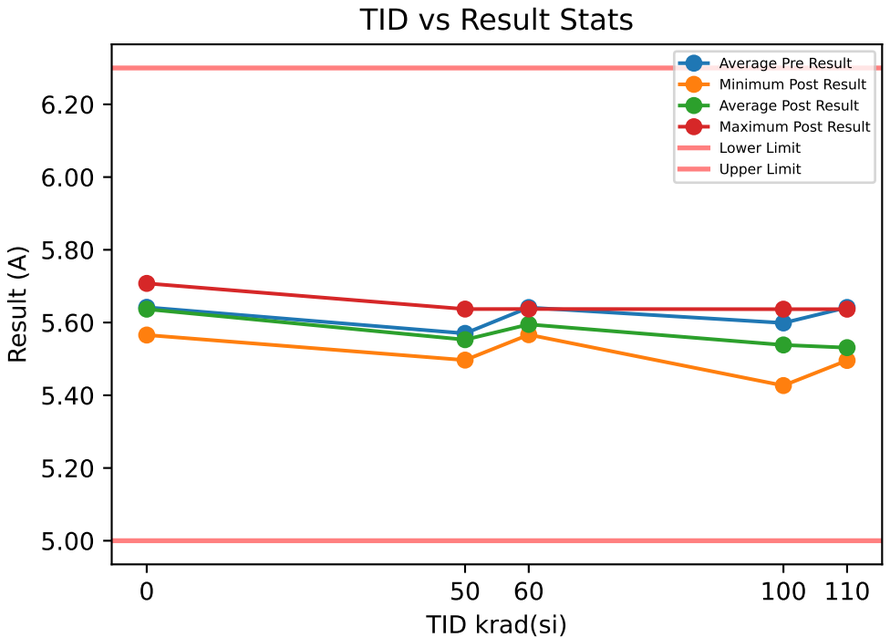
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

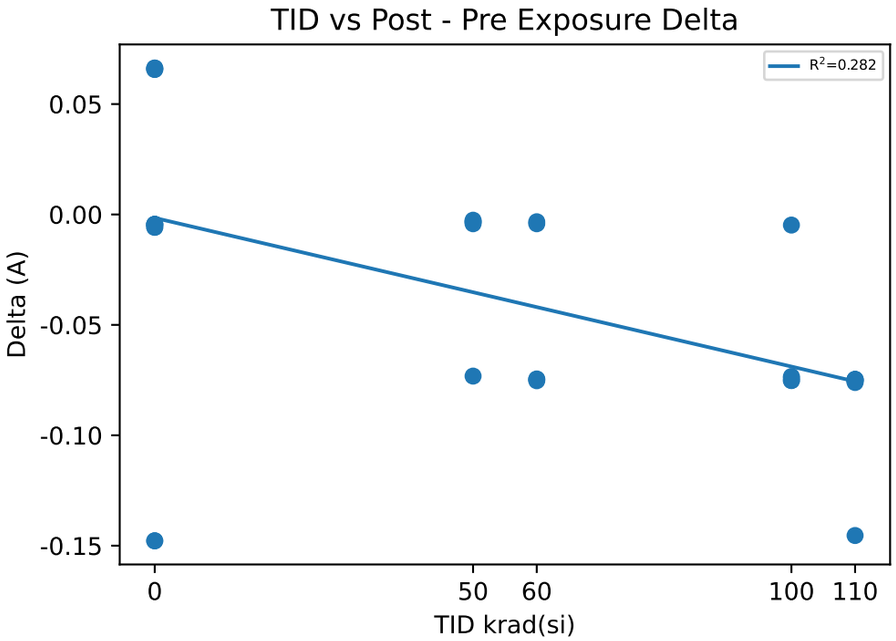
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.6431	5.7096	0.0665
2	0	CU2	5.6438	5.6388	-0.005
3	0	CU3	5.5016	5.4989	-0.0027
11	50	Unbiased-50k	5.5019	5.4988	-0.0031
12	50	Unbiased-50k	5.5723	5.4989	-0.0734
13	50	Unbiased-50k	5.7149	5.6387	-0.0762
14	50	Unbiased-50k	5.5722	5.569	-0.0032
16	50	Unbiased-50k	5.502	5.4987	-0.0033
17	60	Biased-50k	5.5015	5.4296	-0.0719
18	60	Biased-50k	5.5723	5.569	-0.0033
19	60	Biased-50k	5.6435	5.569	-0.0745
20	60	Biased-50k	5.5723	5.5686	-0.0037
21	60	Biased-50k	5.6433	5.5694	-0.0739
24	100	Unbiased-100k	5.5015	5.4965	-0.005
25	100	Unbiased-100k	5.6433	5.6371	-0.0062
26	100	Unbiased-100k	5.7145	5.7076	-0.0069
27	100	Unbiased-100k	5.6434	5.5668	-0.0766
28	100	Unbiased-100k	5.4317	5.427	-0.0047
29	110	Biased-100k	5.6433	5.5665	-0.0768
30	110	Biased-100k	5.7147	5.6369	-0.0778
31	110	Biased-100k	5.5726	5.4963	-0.0763
32	110	Biased-100k	5.6435	5.4963	-0.1472
34	110	Biased-100k	5.5722	5.4963	-0.0759

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5016	5.5962	5.6438	0.081898	5.4989	5.6158	5.7096	0.10722	-0.005	0.0196	0.0665	0.040633
50	5.5019	5.5727	5.7149	0.086937	5.4987	5.5408	5.6387	0.062593	-0.0762	-0.03184	-0.0031	0.039229
60	5.5015	5.5866	5.6435	0.059379	5.4296	5.5411	5.5694	0.062342	-0.0745	-0.04546	-0.0033	0.038316
100	5.4317	5.5869	5.7145	0.11623	5.427	5.567	5.7076	0.11096	-0.0766	-0.01988	-0.0047	0.03172
110	5.5722	5.6293	5.7147	0.059511	5.4963	5.5385	5.6369	0.062867	-0.1472	-0.0908	-0.0759	0.031537

Device Test: 26.4 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW3/3/3///90.9/634//1.8///@HIGH_SIDE_OC)





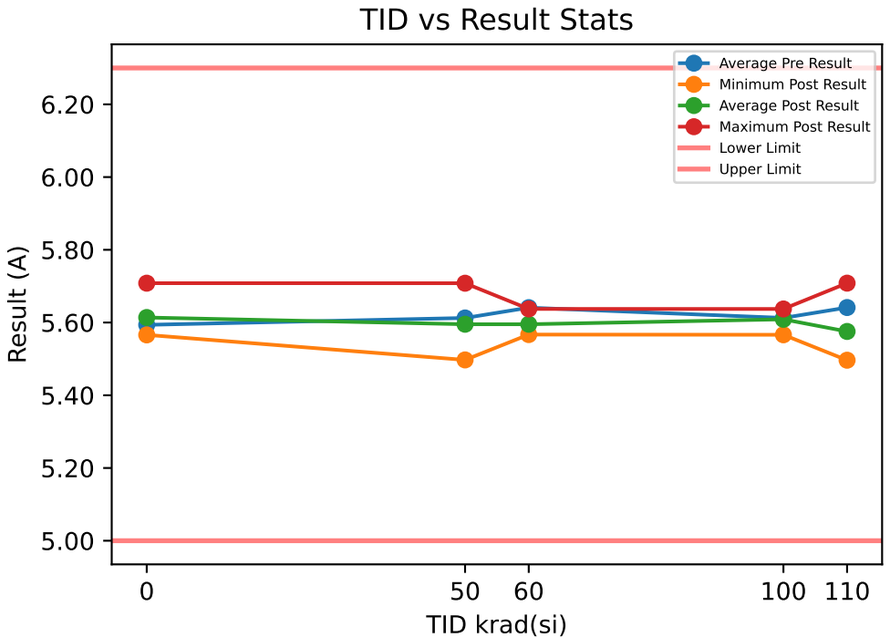
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

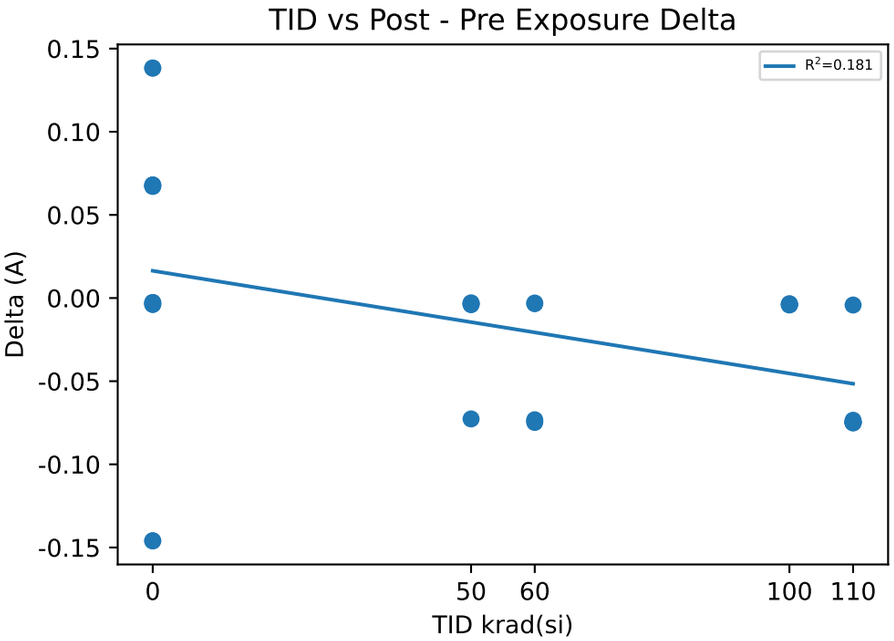
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7134	5.7076	-0.0058
2	0	CU2	5.6411	5.6366	-0.0045
3	0	CU3	5.571	5.5665	-0.0045
11	50	Unbiased-50k	5.5701	5.5669	-0.0032
12	50	Unbiased-50k	5.5699	5.4967	-0.0732
13	50	Unbiased-50k	5.6412	5.637	-0.0042
14	50	Unbiased-50k	5.5701	5.5667	-0.0034
16	50	Unbiased-50k	5.4994	5.4968	-0.0026
17	60	Biased-50k	5.5698	5.5665	-0.0033
18	60	Biased-50k	5.641	5.5665	-0.0745
19	60	Biased-50k	5.7125	5.6372	-0.0753
20	60	Biased-50k	5.6414	5.6372	-0.0042
21	60	Biased-50k	5.6414	5.5667	-0.0747
24	100	Unbiased-100k	5.5698	5.4958	-0.074
25	100	Unbiased-100k	5.6412	5.566	-0.0752
26	100	Unbiased-100k	5.6415	5.6367	-0.0048
27	100	Unbiased-100k	5.6415	5.5663	-0.0752
28	100	Unbiased-100k	5.5001	5.4267	-0.0734
29	110	Biased-100k	5.6412	5.5657	-0.0755
30	110	Biased-100k	5.7128	5.6367	-0.0761
31	110	Biased-100k	5.6414	5.566	-0.0754
32	110	Biased-100k	5.6412	5.4958	-0.1454
34	110	Biased-100k	5.5705	5.4957	-0.0748

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.571	5.6418	5.7134	0.071203	5.5665	5.6369	5.7076	0.07055	-0.0058	-0.0049333	-0.0045	0.00075056
50	5.4994	5.5701	5.6412	0.050134	5.4967	5.5528	5.637	0.058662	-0.0732	-0.01732	-0.0026	0.031243
60	5.5698	5.6412	5.7125	0.050452	5.5665	5.5948	5.6372	0.038688	-0.0753	-0.0464	-0.0033	0.038936
100	5.5001	5.5988	5.6415	0.063299	5.4267	5.5383	5.6367	0.079835	-0.0752	-0.06052	-0.0048	0.031158
110	5.5705	5.6414	5.7128	0.050311	5.4957	5.552	5.6367	0.058919	-0.1454	-0.08944	-0.0748	0.031286

Device Test: 26.5 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW4/3/3///90.9/634//1.8///@HIGH_SIDE_OC)





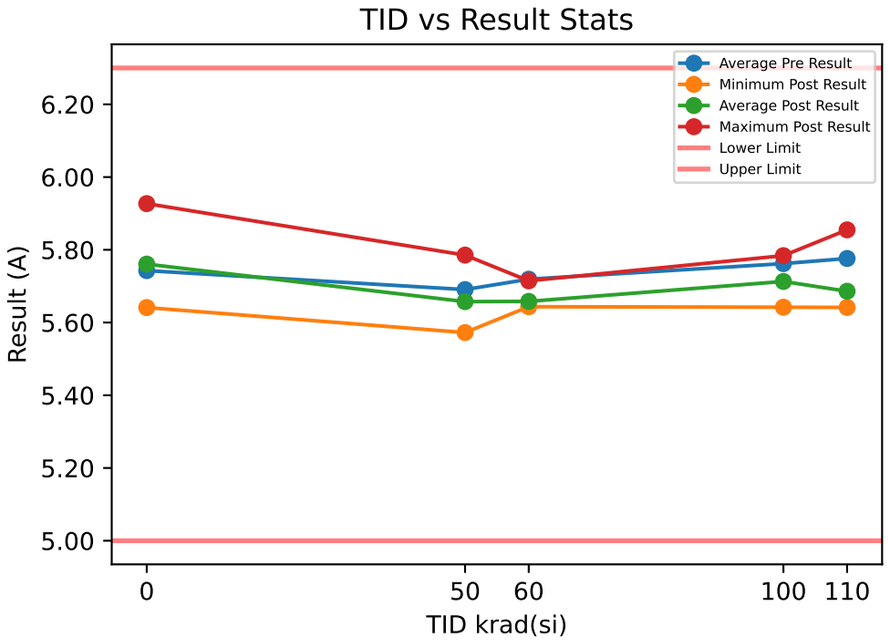
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

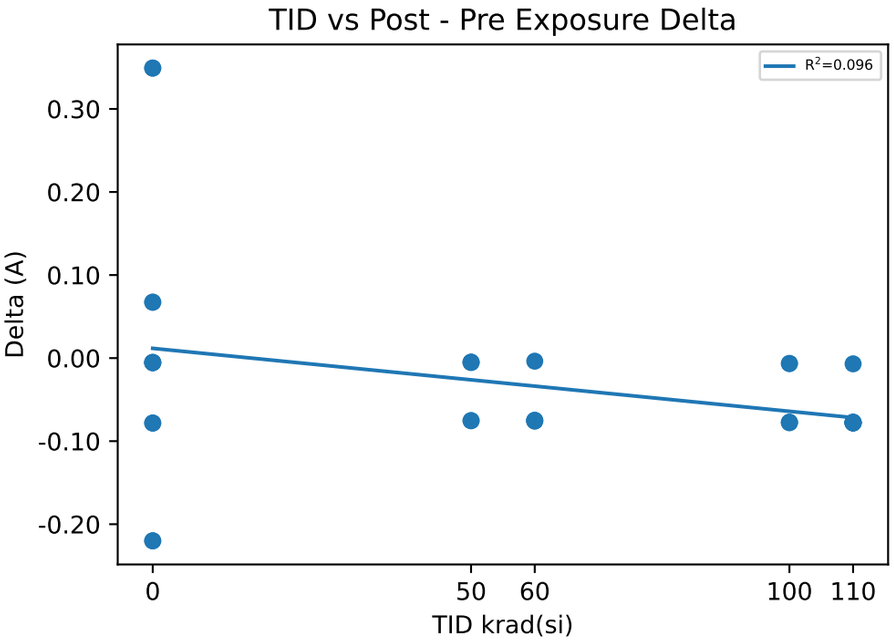
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.712	5.7082	-0.0038
2	0	CU2	5.5698	5.5671	-0.0027
3	0	CU3	5.4991	5.5671	0.068
11	50	Unbiased-50k	5.5702	5.5669	-0.0033
12	50	Unbiased-50k	5.5699	5.4972	-0.0727
13	50	Unbiased-50k	5.7121	5.7081	-0.004
14	50	Unbiased-50k	5.6407	5.6373	-0.0034
16	50	Unbiased-50k	5.5698	5.5669	-0.0029
17	60	Biased-50k	5.6407	5.5675	-0.0732
18	60	Biased-50k	5.641	5.5671	-0.0739
19	60	Biased-50k	5.6408	5.6374	-0.0034
20	60	Biased-50k	5.7121	5.6373	-0.0748
21	60	Biased-50k	5.5699	5.5669	-0.003
24	100	Unbiased-100k	5.5697	5.5663	-0.0034
25	100	Unbiased-100k	5.641	5.6372	-0.0038
26	100	Unbiased-100k	5.6412	5.6371	-0.0041
27	100	Unbiased-100k	5.6414	5.6373	-0.0041
28	100	Unbiased-100k	5.5703	5.5664	-0.0039
29	110	Biased-100k	5.5699	5.4964	-0.0735
30	110	Biased-100k	5.7125	5.7083	-0.0042
31	110	Biased-100k	5.6412	5.5663	-0.0749
32	110	Biased-100k	5.6414	5.5663	-0.0751
34	110	Biased-100k	5.6412	5.5665	-0.0747

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4991	5.5936	5.712	0.10843	5.5671	5.6141	5.7082	0.081464	-0.0038	0.0205	0.068	0.04114
50	5.5698	5.6125	5.7121	0.063527	5.4972	5.5953	5.7081	0.080194	-0.0727	-0.01726	-0.0029	0.030994
60	5.5699	5.6409	5.7121	0.050275	5.5669	5.5952	5.6374	0.038442	-0.0748	-0.04566	-0.003	0.038765
100	5.5697	5.6127	5.6414	0.038999	5.5663	5.6089	5.6373	0.038806	-0.0041	-0.00386	-0.0034	0.0002881
110	5.5699	5.6412	5.7125	0.050417	5.4964	5.5808	5.7083	0.077467	-0.0751	-0.06048	-0.0042	0.031468

Device Test: 27.2 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW1/7/7///90.9/634//1.8///@HIGH_SIDE_OC)





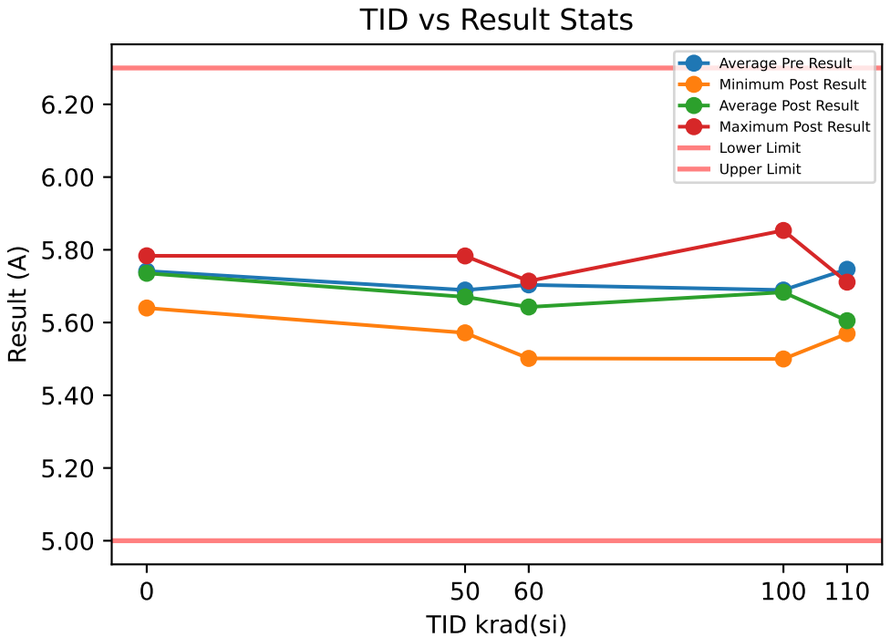
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

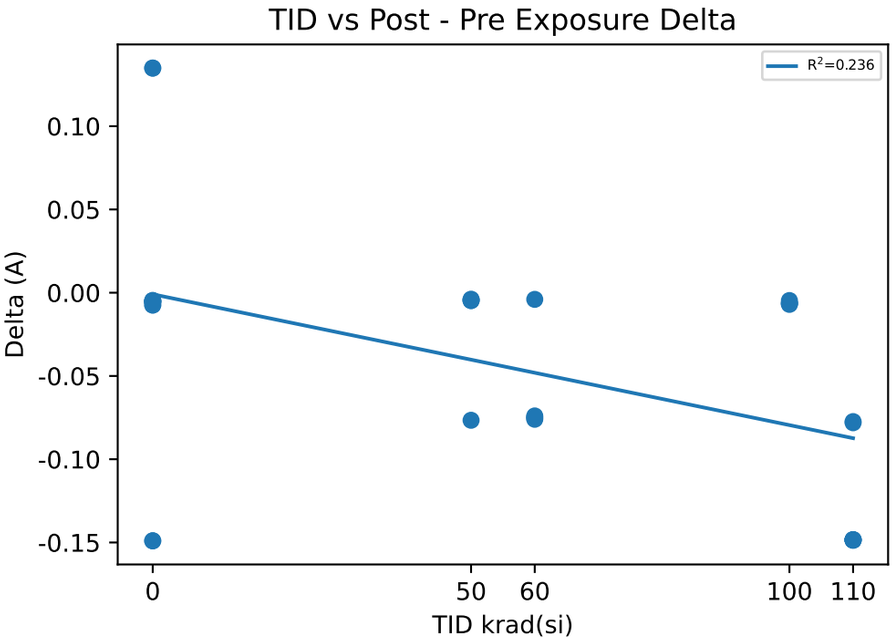
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9322	5.927	-0.0052
2	0	CU2	5.5766	5.6439	0.0673
3	0	CU3	5.7194	5.7139	-0.0055
11	50	Unbiased-50k	5.648	5.6431	-0.0049
12	50	Unbiased-50k	5.6477	5.5724	-0.0753
13	50	Unbiased-50k	5.7192	5.7139	-0.0053
14	50	Unbiased-50k	5.7904	5.7854	-0.005
16	50	Unbiased-50k	5.6479	5.5725	-0.0754
17	60	Biased-50k	5.6476	5.6439	-0.0037
18	60	Biased-50k	5.7194	5.6446	-0.0748
19	60	Biased-50k	5.7194	5.6441	-0.0753
20	60	Biased-50k	5.79	5.7146	-0.0754
21	60	Biased-50k	5.7194	5.6435	-0.0759
24	100	Unbiased-100k	5.7192	5.6421	-0.0771
25	100	Unbiased-100k	5.7906	5.7131	-0.0775
26	100	Unbiased-100k	5.7194	5.7129	-0.0065
27	100	Unbiased-100k	5.7904	5.7126	-0.0778
28	100	Unbiased-100k	5.7904	5.7839	-0.0065
29	110	Biased-100k	5.7194	5.6417	-0.0777
30	110	Biased-100k	5.9318	5.8548	-0.077
31	110	Biased-100k	5.7906	5.7127	-0.0779
32	110	Biased-100k	5.7194	5.7125	-0.0069
34	110	Biased-100k	5.7195	5.6417	-0.0778

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5766	5.7427	5.9322	0.17894	5.6439	5.7616	5.927	0.14745	-0.0055	0.018867	0.0673	0.041945
50	5.6477	5.6906	5.7904	0.06375	5.5724	5.6575	5.7854	0.092485	-0.0754	-0.03318	-0.0049	0.038496
60	5.6476	5.7192	5.79	0.050347	5.6435	5.6581	5.7146	0.031565	-0.0759	-0.06102	-0.0037	0.032045
100	5.7192	5.762	5.7906	0.03898	5.6421	5.7129	5.7839	0.050134	-0.0778	-0.04908	-0.0065	0.038871
110	5.7194	5.7761	5.9318	0.092312	5.6417	5.7127	5.8548	0.086998	-0.0779	-0.06346	-0.0069	0.03162

Device Test: 27.3 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW2/7/7///90.9/634//1.8///@HIGH_SIDE_OC)





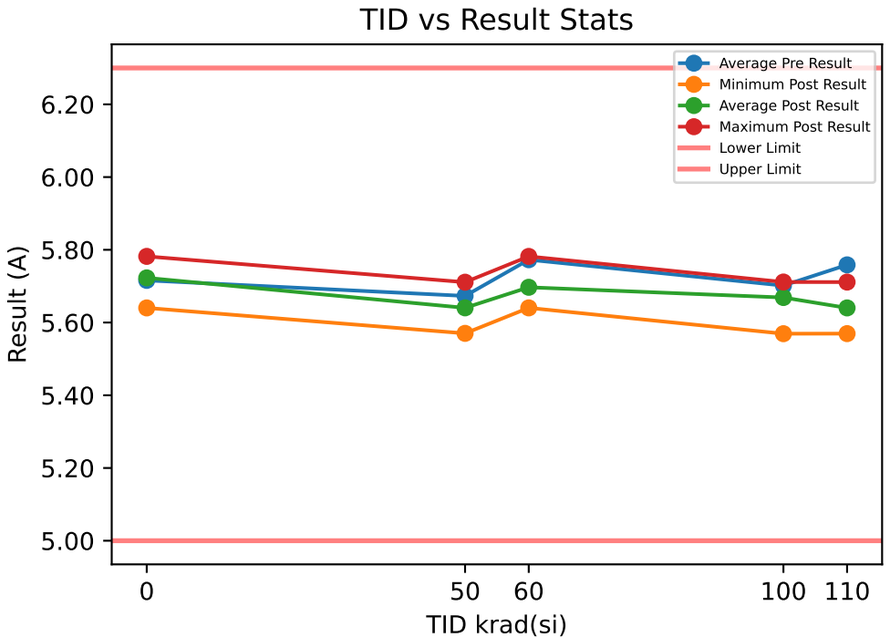
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

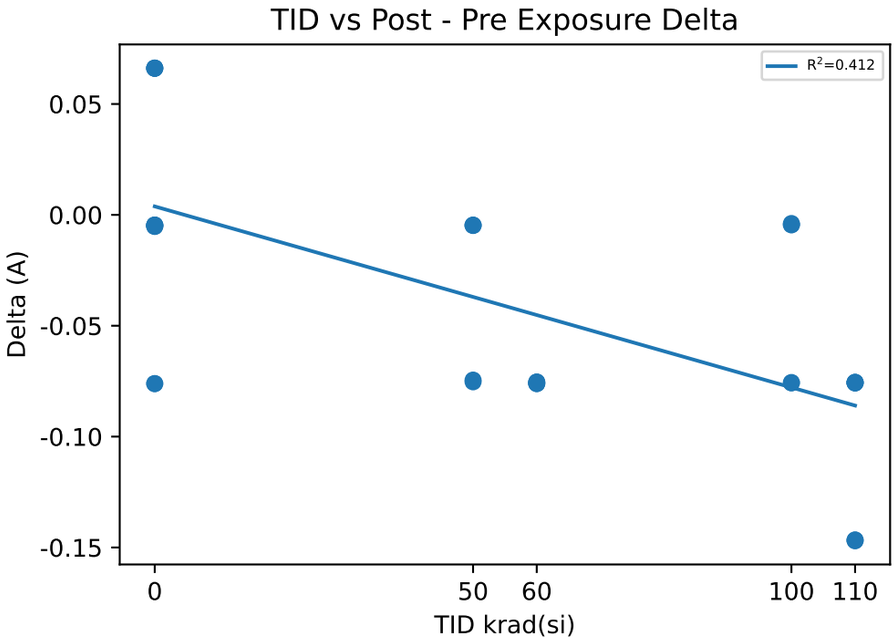
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.7889	5.7835	-0.0054
2	0	CU2	5.7889	5.7835	-0.0054
3	0	CU3	5.6468	5.6421	-0.0047
11	50	Unbiased-50k	5.6468	5.6421	-0.0047
12	50	Unbiased-50k	5.6468	5.6421	-0.0047
13	50	Unbiased-50k	5.8597	5.7831	-0.0766
14	50	Unbiased-50k	5.7179	5.7136	-0.0043
16	50	Unbiased-50k	5.5756	5.5717	-0.0039
17	60	Biased-50k	5.5753	5.5013	-0.074
18	60	Biased-50k	5.7175	5.6429	-0.0746
19	60	Biased-50k	5.7889	5.7129	-0.076
20	60	Biased-50k	5.718	5.6426	-0.0754
21	60	Biased-50k	5.718	5.714	-0.004
24	100	Unbiased-100k	5.6468	5.6408	-0.006
25	100	Unbiased-100k	5.7178	5.7113	-0.0065
26	100	Unbiased-100k	5.8597	5.8532	-0.0065
27	100	Unbiased-100k	5.7182	5.7112	-0.007
28	100	Unbiased-100k	5.5045	5.4998	-0.0047
29	110	Biased-100k	5.789	5.6403	-0.1487
30	110	Biased-100k	5.7891	5.711	-0.0781
31	110	Biased-100k	5.6469	5.5695	-0.0774
32	110	Biased-100k	5.789	5.6405	-0.1485
34	110	Biased-100k	5.7182	5.5697	-0.1485

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6468	5.7415	5.7889	0.082041	5.6421	5.7364	5.7835	0.081637	-0.0054	-0.0051667	-0.0047	0.00040415
50	5.5756	5.6894	5.8597	0.1077	5.5717	5.6705	5.7831	0.080484	-0.0766	-0.01884	-0.0039	0.032291
60	5.5753	5.7035	5.7889	0.078014	5.5013	5.6427	5.714	0.086611	-0.076	-0.0608	-0.004	0.031761
100	5.5045	5.6894	5.8597	0.12907	5.4998	5.6833	5.8532	0.12836	-0.007	-0.00614	-0.0047	0.0008792
110	5.6469	5.7464	5.7891	0.063538	5.5695	5.6262	5.711	0.059164	-0.1487	-0.12024	-0.0774	0.038789

Device Test: 27.4 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW3/7/7///90.9/634//1.8///@HIGH_SIDE_OC)





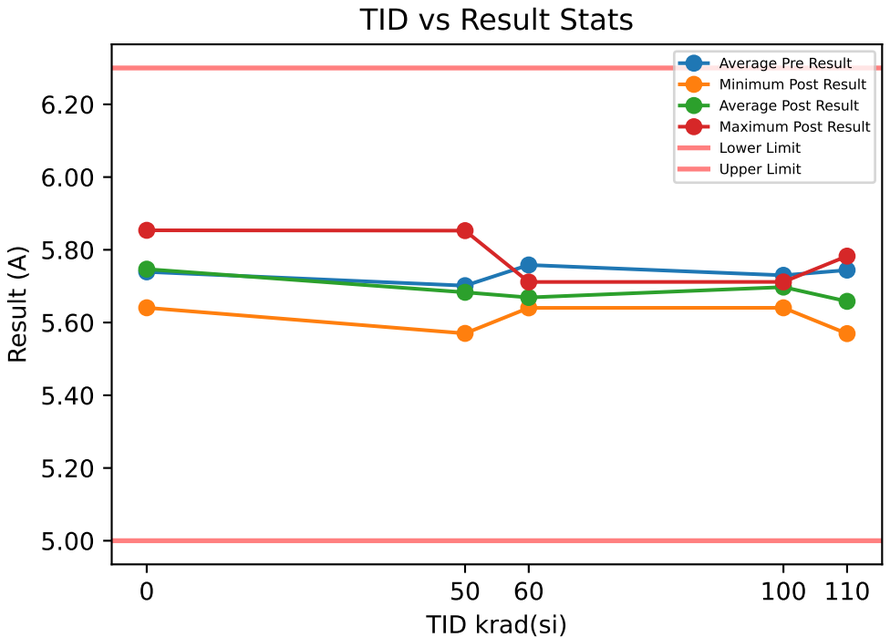
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

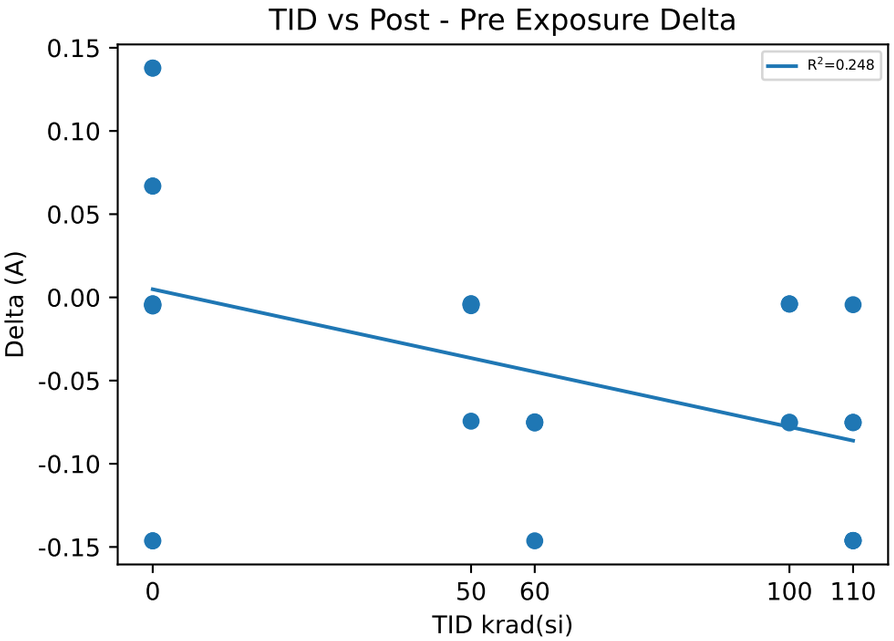
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.787	5.7818	-0.0052
2	0	CU2	5.7158	5.7111	-0.0047
3	0	CU3	5.6448	5.6402	-0.0046
11	50	Unbiased-50k	5.7158	5.6405	-0.0753
12	50	Unbiased-50k	5.6448	5.6402	-0.0046
13	50	Unbiased-50k	5.7157	5.7109	-0.0048
14	50	Unbiased-50k	5.6448	5.6401	-0.0047
16	50	Unbiased-50k	5.6447	5.5702	-0.0745
17	60	Biased-50k	5.7157	5.6403	-0.0754
18	60	Biased-50k	5.7159	5.6405	-0.0754
19	60	Biased-50k	5.8579	5.7818	-0.0761
20	60	Biased-50k	5.787	5.711	-0.076
21	60	Biased-50k	5.787	5.711	-0.076
24	100	Unbiased-100k	5.6445	5.6406	-0.0039
25	100	Unbiased-100k	5.7868	5.7112	-0.0756
26	100	Unbiased-100k	5.7158	5.7114	-0.0044
27	100	Unbiased-100k	5.7871	5.7113	-0.0758
28	100	Unbiased-100k	5.5738	5.5693	-0.0045
29	110	Biased-100k	5.7871	5.6401	-0.147
30	110	Biased-100k	5.8579	5.7112	-0.1467
31	110	Biased-100k	5.7159	5.6404	-0.0755
32	110	Biased-100k	5.7161	5.5695	-0.1466
34	110	Biased-100k	5.7158	5.6402	-0.0756

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6448	5.7159	5.787	0.0711	5.6402	5.711	5.7818	0.0708	-0.0052	-0.0048333	-0.0046	0.00032146
50	5.6447	5.6732	5.7158	0.038879	5.5702	5.6404	5.7109	0.049745	-0.0753	-0.03278	-0.0046	0.038451
60	5.7157	5.7727	5.8579	0.059463	5.6403	5.6969	5.7818	0.05914	-0.0761	-0.07578	-0.0754	0.00034928
100	5.5738	5.7016	5.7871	0.092688	5.5693	5.6688	5.7114	0.063471	-0.0758	-0.03284	-0.0039	0.039126
110	5.7158	5.7586	5.8579	0.06351	5.5695	5.6403	5.7112	0.050099	-0.147	-0.11828	-0.0755	0.039007

Device Test: 27.5 HIGH_SIDE_OC(ILIM_HS|HS_Sourcing/SW4/7/7///90.9/634//1.8///@HIGH_SIDE_OC)





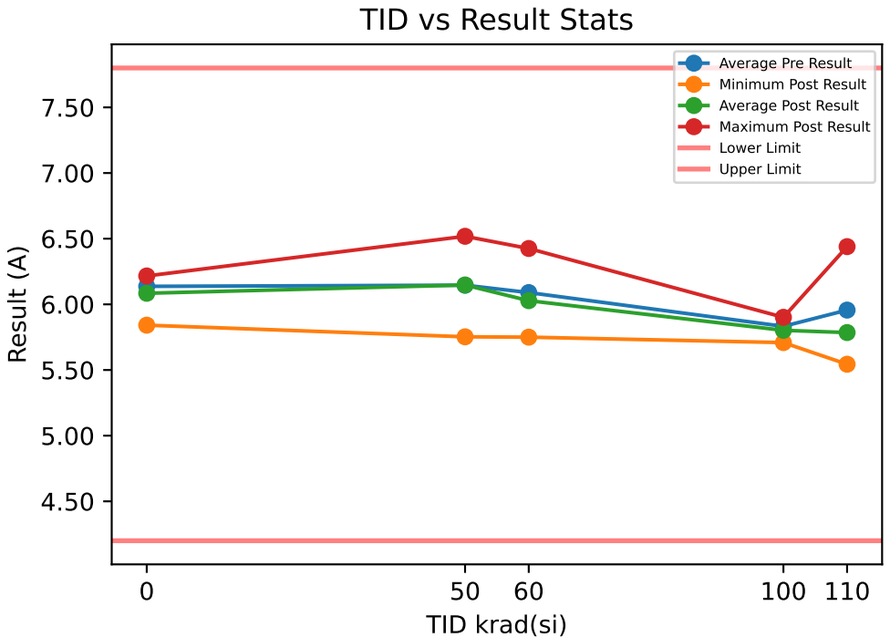
Test Results (Lower Limit = 5.0, Upper Limit = 6.3 (A))

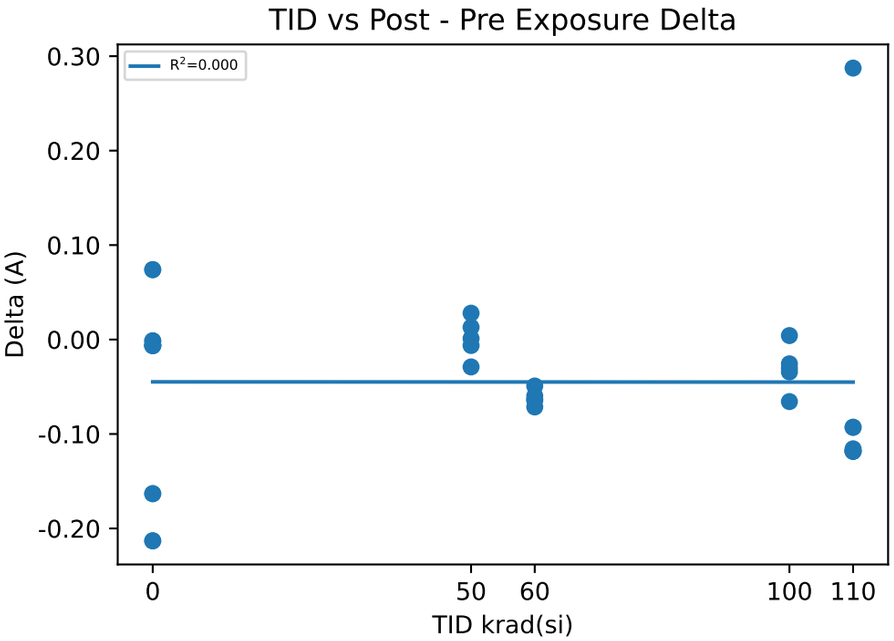
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8576	5.8525	-0.0051
2	0	CU2	5.7158	5.7113	-0.0045
3	0	CU3	5.6445	5.6406	-0.0039
11	50	Unbiased-50k	5.6445	5.6405	-0.004
12	50	Unbiased-50k	5.6445	5.5701	-0.0744
13	50	Unbiased-50k	5.8577	5.8527	-0.005
14	50	Unbiased-50k	5.7157	5.7114	-0.0043
16	50	Unbiased-50k	5.6445	5.6407	-0.0038
17	60	Biased-50k	5.7155	5.6403	-0.0752
18	60	Biased-50k	5.7157	5.6409	-0.0748
19	60	Biased-50k	5.8577	5.7114	-0.1463
20	60	Biased-50k	5.787	5.7115	-0.0755
21	60	Biased-50k	5.7155	5.6405	-0.075
24	100	Unbiased-100k	5.6444	5.6405	-0.0039
25	100	Unbiased-100k	5.7866	5.7116	-0.075
26	100	Unbiased-100k	5.787	5.7116	-0.0754
27	100	Unbiased-100k	5.7157	5.7117	-0.004
28	100	Unbiased-100k	5.7157	5.7117	-0.004
29	110	Biased-100k	5.6447	5.5695	-0.0752
30	110	Biased-100k	5.8577	5.7826	-0.0751
31	110	Biased-100k	5.7159	5.6406	-0.0753
32	110	Biased-100k	5.7157	5.7113	-0.0044
34	110	Biased-100k	5.7867	5.6406	-0.1461

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6445	5.7393	5.8576	0.10848	5.6406	5.7348	5.8525	0.10789	-0.0051	-0.0045	-0.0039	0.0006
50	5.6445	5.7014	5.8577	0.092665	5.5701	5.6831	5.8527	0.10718	-0.0744	-0.0183	-0.0038	0.031364
60	5.7155	5.7583	5.8577	0.063605	5.6403	5.6689	5.7115	0.038825	-0.1463	-0.08936	-0.0748	0.031831
100	5.6444	5.7299	5.787	0.059558	5.6405	5.6974	5.7117	0.031819	-0.0754	-0.03246	-0.0039	0.039016
110	5.6447	5.7441	5.8577	0.080935	5.5695	5.6689	5.7826	0.080944	-0.1461	-0.07522	-0.0044	0.050099

Device Test: 28.2 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW1/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





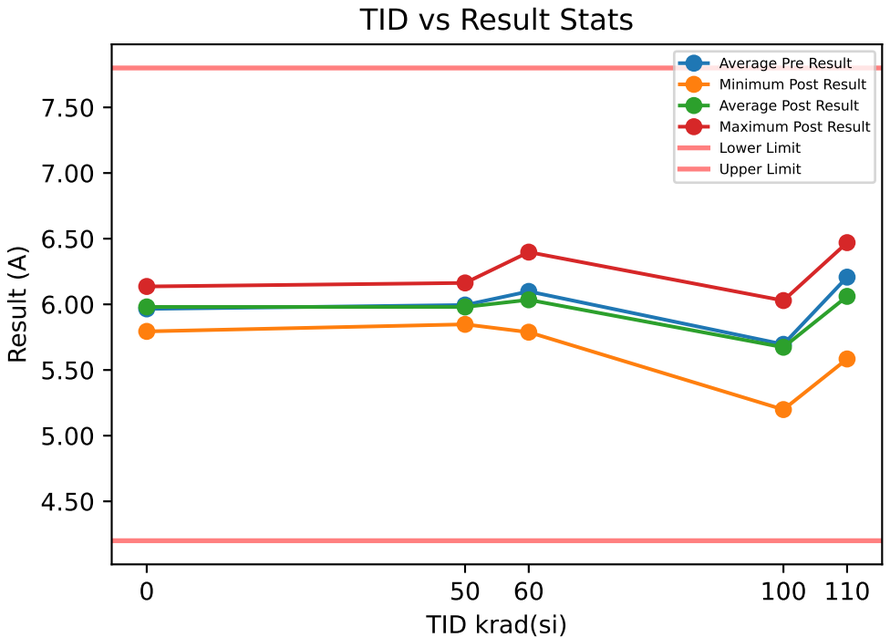
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

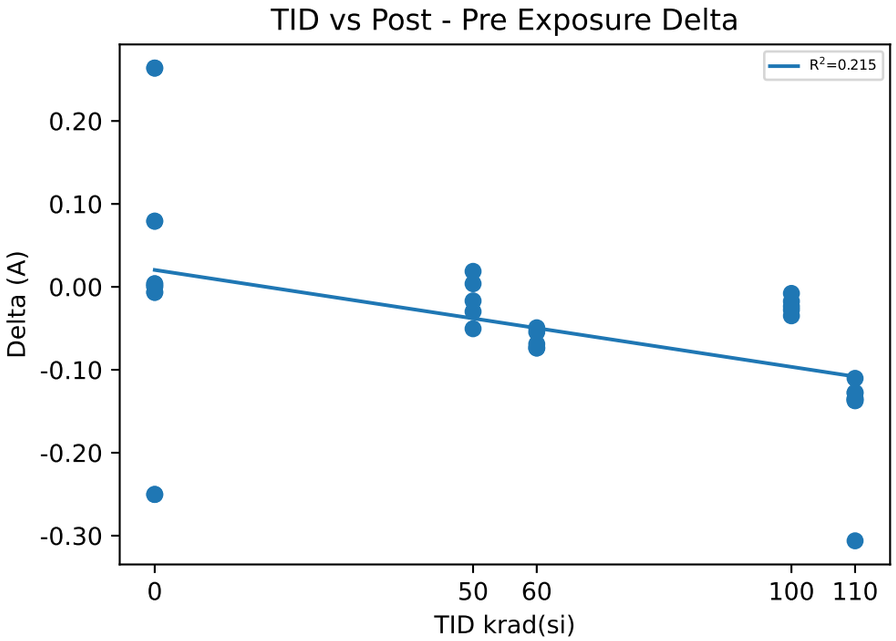
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0545	6.0484	-0.0061
2	0	CU2	6.2145	6.2131	-0.0014
3	0	CU3	6.1422	6.1357	-0.0065
11	50	Unbiased-50k	5.7591	5.7528	-0.0063
12	50	Unbiased-50k	6.0296	6.0575	0.0279
13	50	Unbiased-50k	6.1544	6.1254	-0.029
14	50	Unbiased-50k	6.5052	6.5182	0.013
16	50	Unbiased-50k	6.2808	6.2819	0.0011
17	60	Biased-50k	6.485	6.4253	-0.0597
18	60	Biased-50k	6.0518	5.9804	-0.0714
19	60	Biased-50k	6.1422	6.093	-0.0492
20	60	Biased-50k	5.9546	5.8911	-0.0635
21	60	Biased-50k	5.8144	5.7501	-0.0643
24	100	Unbiased-100k	5.8851	5.8508	-0.0343
25	100	Unbiased-100k	5.927	5.9013	-0.0257
26	100	Unbiased-100k	5.7046	5.7088	0.0042
27	100	Unbiased-100k	5.8717	5.8414	-0.0303
28	100	Unbiased-100k	5.7745	5.7088	-0.0657
29	110	Biased-100k	5.6438	5.551	-0.0928
30	110	Biased-100k	6.2591	6.1661	-0.093
31	110	Biased-100k	6.064	5.9483	-0.1157
32	110	Biased-100k	6.1521	6.4395	0.2874
34	110	Biased-100k	5.6623	5.5443	-0.118

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0545	6.1371	6.2145	0.080123	6.0484	6.1324	6.2131	0.0824	-0.0065	-0.0046667	-0.0014	0.0028361
50	5.7591	6.1458	6.5052	0.27862	5.7528	6.1472	6.5182	0.28278	-0.029	0.00134	0.0279	0.021333
60	5.8144	6.0896	6.485	0.25224	5.7501	6.028	6.4253	0.2551	-0.0714	-0.06162	-0.0492	0.0081288
100	5.7046	5.8326	5.927	0.090769	5.7088	5.8022	5.9013	0.08827	-0.0657	-0.03036	0.0042	0.024903
110	5.6438	5.9563	6.2591	0.28536	5.5443	5.9298	6.4395	0.3899	-0.118	-0.02642	0.2874	0.17584

Device Test: 28.3 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW2/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





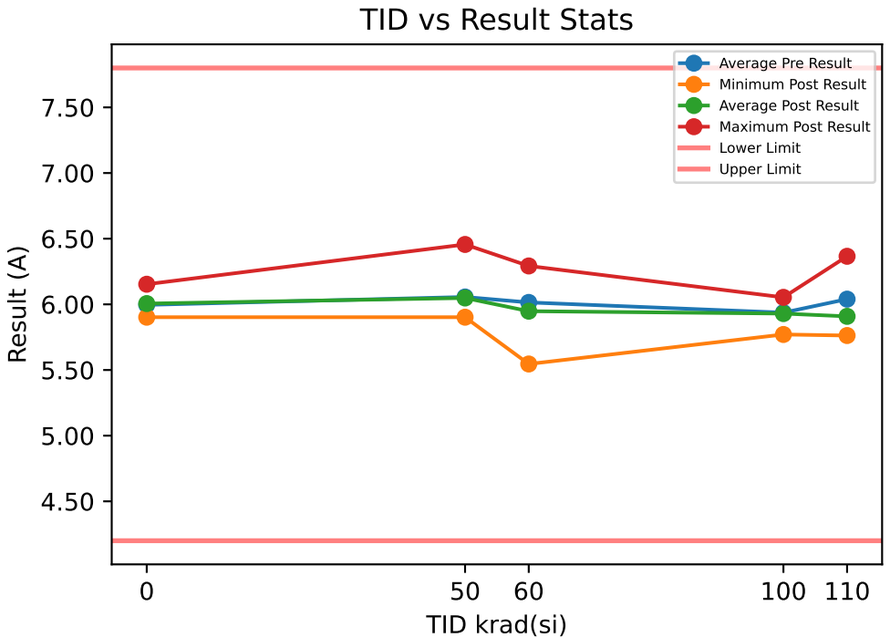
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

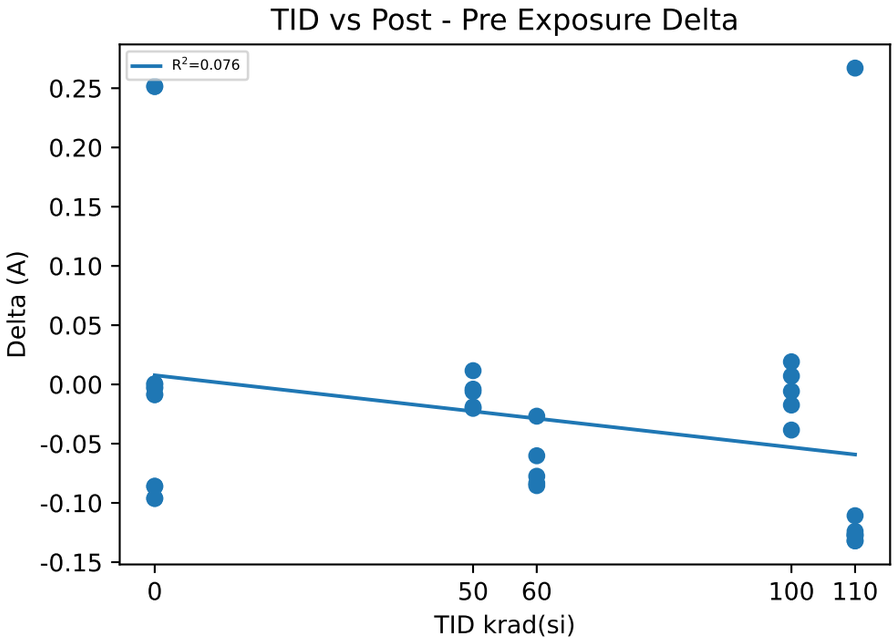
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0569	6.0606	0.0037
2	0	CU2	5.795	5.7955	0.0005
3	0	CU3	6.0443	6.0377	-0.0066
11	50	Unbiased-50k	5.829	5.8477	0.0187
12	50	Unbiased-50k	5.9744	5.9239	-0.0505
13	50	Unbiased-50k	6.1323	6.1025	-0.0298
14	50	Unbiased-50k	6.1592	6.163	0.0038
16	50	Unbiased-50k	5.8796	5.8627	-0.0169
17	60	Biased-50k	6.1418	6.0681	-0.0737
18	60	Biased-50k	6.062	5.9931	-0.0689
19	60	Biased-50k	6.4522	6.3977	-0.0545
20	60	Biased-50k	5.9992	5.9255	-0.0737
21	60	Biased-50k	5.8373	5.788	-0.0493
24	100	Unbiased-100k	5.6315	5.6236	-0.0079
25	100	Unbiased-100k	5.7469	5.7234	-0.0235
26	100	Unbiased-100k	6.0565	6.0288	-0.0277
27	100	Unbiased-100k	5.2161	5.1987	-0.0174
28	100	Unbiased-100k	5.8266	5.7917	-0.0349
29	110	Biased-100k	6.177	6.0493	-0.1277
30	110	Biased-100k	6.5802	6.4699	-0.1103
31	110	Biased-100k	5.7117	5.5841	-0.1276
32	110	Biased-100k	6.3448	6.0386	-0.3062
34	110	Biased-100k	6.222	6.0872	-0.1348

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.795	5.9654	6.0569	0.14771	5.7955	5.9646	6.0606	0.14689	-0.0066	-0.0008	0.0037	0.0052716
50	5.829	5.9949	6.1592	0.14757	5.8477	5.98	6.163	0.14397	-0.0505	-0.01494	0.0187	0.027258
60	5.8373	6.0985	6.4522	0.22715	5.788	6.0345	6.3977	0.22771	-0.0737	-0.06402	-0.0493	0.011386
100	5.2161	5.6955	6.0565	0.30987	5.1987	5.6732	6.0288	0.30439	-0.0349	-0.02228	-0.0079	0.010256
110	5.7117	6.2071	6.5802	0.31809	5.5841	6.0458	6.4699	0.31417	-0.3062	-0.16132	-0.1103	0.081492

Device Test: 28.4 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW3/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





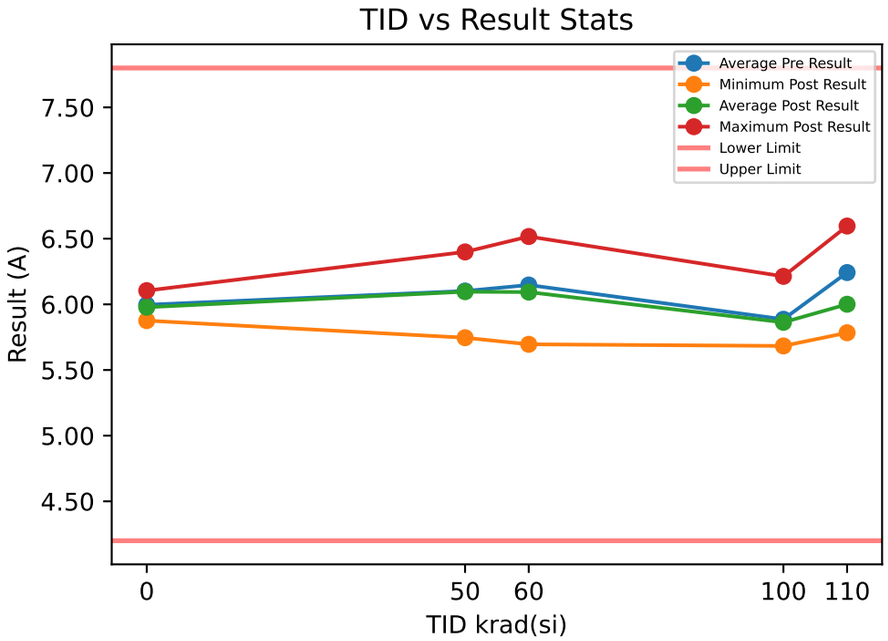
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

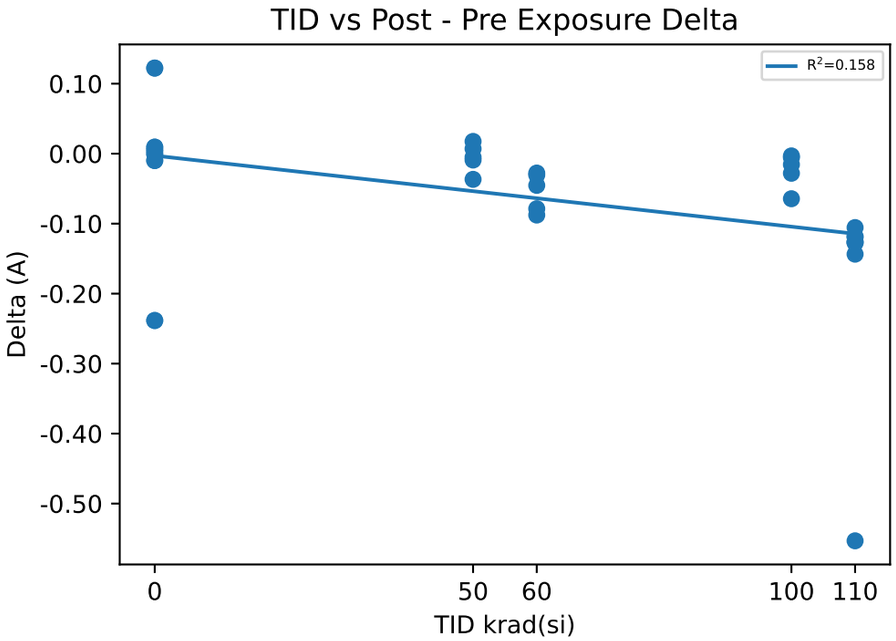
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9017	5.9021	0.0004
2	0	CU2	5.9994	5.9966	-0.0028
3	0	CU3	6.0871	6.0785	-0.0086
11	50	Unbiased-50k	5.929	5.9088	-0.0202
12	50	Unbiased-50k	5.9235	5.9045	-0.019
13	50	Unbiased-50k	5.9061	5.9021	-0.004
14	50	Unbiased-50k	6.4445	6.4561	0.0116
16	50	Unbiased-50k	6.0769	6.0709	-0.006
17	60	Biased-50k	6.0895	6.0061	-0.0834
18	60	Biased-50k	6.0871	6.0017	-0.0854
19	60	Biased-50k	6.3192	6.2924	-0.0268
20	60	Biased-50k	5.9713	5.8938	-0.0775
21	60	Biased-50k	5.606	5.5458	-0.0602
24	100	Unbiased-100k	5.999	5.9605	-0.0385
25	100	Unbiased-100k	6.0591	6.0533	-0.0058
26	100	Unbiased-100k	5.7634	5.7705	0.0071
27	100	Unbiased-100k	5.8535	5.8361	-0.0174
28	100	Unbiased-100k	6.0093	6.0284	0.0191
29	110	Biased-100k	5.9436	5.8155	-0.1281
30	110	Biased-100k	6.369	6.2582	-0.1108
31	110	Biased-100k	5.8922	5.7682	-0.124
32	110	Biased-100k	6.099	6.366	0.267
34	110	Biased-100k	5.8946	5.7626	-0.132

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9017	5.9961	6.0871	0.092745	5.9021	5.9924	6.0785	0.088275	-0.0086	-0.0036667	0.0004	0.0045622
50	5.9061	6.056	6.4445	0.22777	5.9021	6.0485	6.4561	0.23892	-0.0202	-0.00752	0.0116	0.01297
60	5.606	6.0146	6.3192	0.261	5.5458	5.948	6.2924	0.26906	-0.0854	-0.06666	-0.0268	0.02439
100	5.7634	5.9369	6.0591	0.12358	5.7705	5.9298	6.0533	0.12255	-0.0385	-0.0071	0.0191	0.022259
110	5.8922	6.0397	6.369	0.20248	5.7626	5.9941	6.366	0.2935	-0.132	-0.04558	0.267	0.17492

Device Test: 28.5 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW4/3/3///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





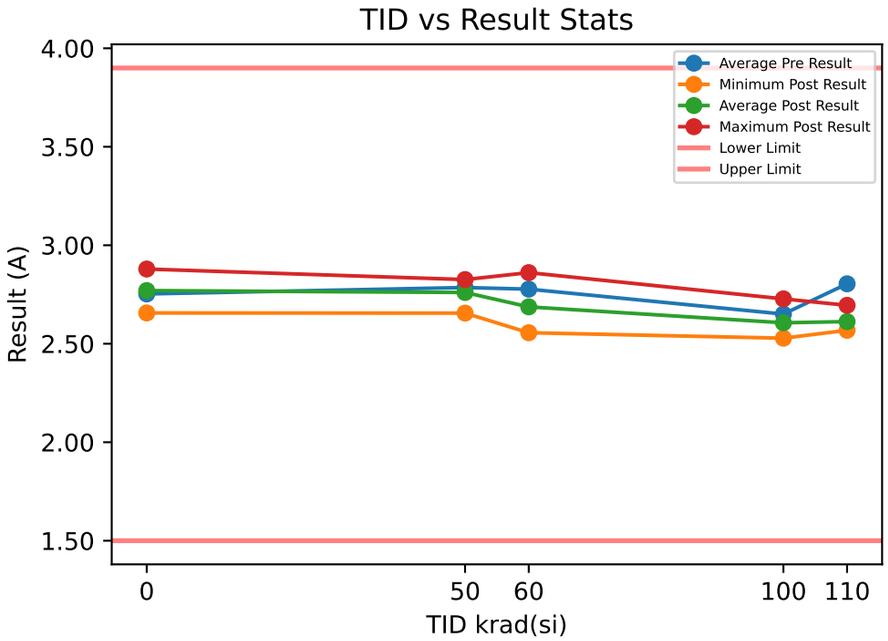
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

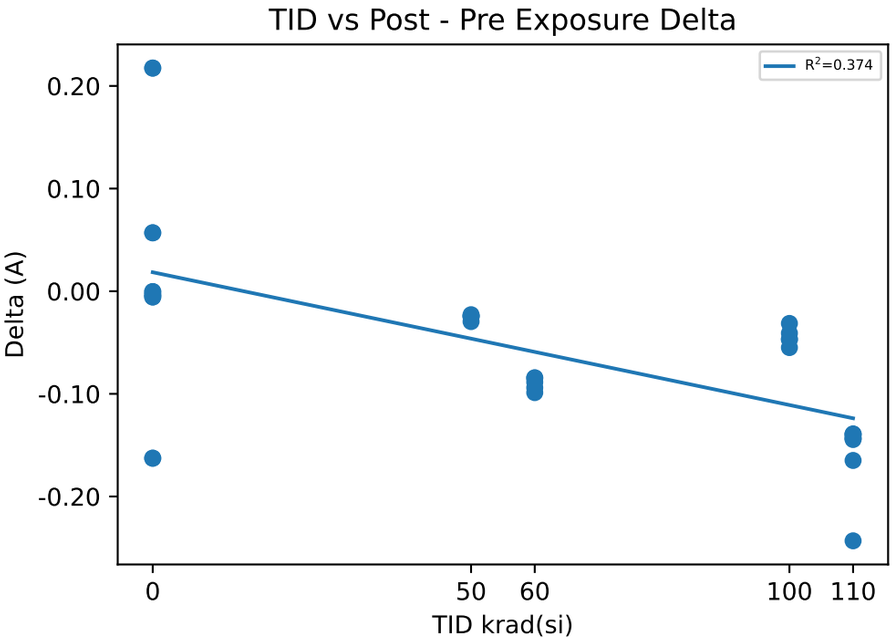
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9966	6.0013	0.0047
2	0	CU2	5.8788	5.8784	-0.0004
3	0	CU3	6.1144	6.1046	-0.0098
11	50	Unbiased-50k	5.7389	5.7459	0.007
12	50	Unbiased-50k	5.8871	5.878	-0.0091
13	50	Unbiased-50k	6.4042	6.3991	-0.0051
14	50	Unbiased-50k	6.3413	6.3588	0.0175
16	50	Unbiased-50k	6.1365	6.0998	-0.0367
17	60	Biased-50k	6.0239	5.9962	-0.0277
18	60	Biased-50k	6.3389	6.2512	-0.0877
19	60	Biased-50k	6.5619	6.5166	-0.0453
20	60	Biased-50k	6.0852	6.0065	-0.0787
21	60	Biased-50k	5.7262	5.6957	-0.0305
24	100	Unbiased-100k	6.2164	6.2132	-0.0032
25	100	Unbiased-100k	5.6989	5.6833	-0.0156
26	100	Unbiased-100k	5.861	5.8554	-0.0056
27	100	Unbiased-100k	5.7713	5.7433	-0.028
28	100	Unbiased-100k	5.8843	5.8199	-0.0644
29	110	Biased-100k	6.0717	5.9281	-0.1436
30	110	Biased-100k	6.7018	6.5962	-0.1056
31	110	Biased-100k	5.9112	5.7836	-0.1276
32	110	Biased-100k	6.454	5.9008	-0.5532
34	110	Biased-100k	6.0717	5.953	-0.1187

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8788	5.9966	6.1144	0.1178	5.8784	5.9948	6.1046	0.11324	-0.0098	-0.0018333	0.0047	0.0073555
50	5.7389	6.1016	6.4042	0.28627	5.7459	6.0963	6.3991	0.28768	-0.0367	-0.00528	0.0175	0.020442
60	5.7262	6.1472	6.5619	0.3182	5.6957	6.0932	6.5166	0.30788	-0.0877	-0.05398	-0.0277	0.027683
100	5.6989	5.8864	6.2164	0.19872	5.6833	5.863	6.2132	0.20687	-0.0644	-0.02336	-0.0032	0.024939
110	5.9112	6.2421	6.7018	0.3255	5.7836	6.0323	6.5962	0.32182	-0.5532	-0.20974	-0.1056	0.1925

Device Test: 28.6 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW1/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK)





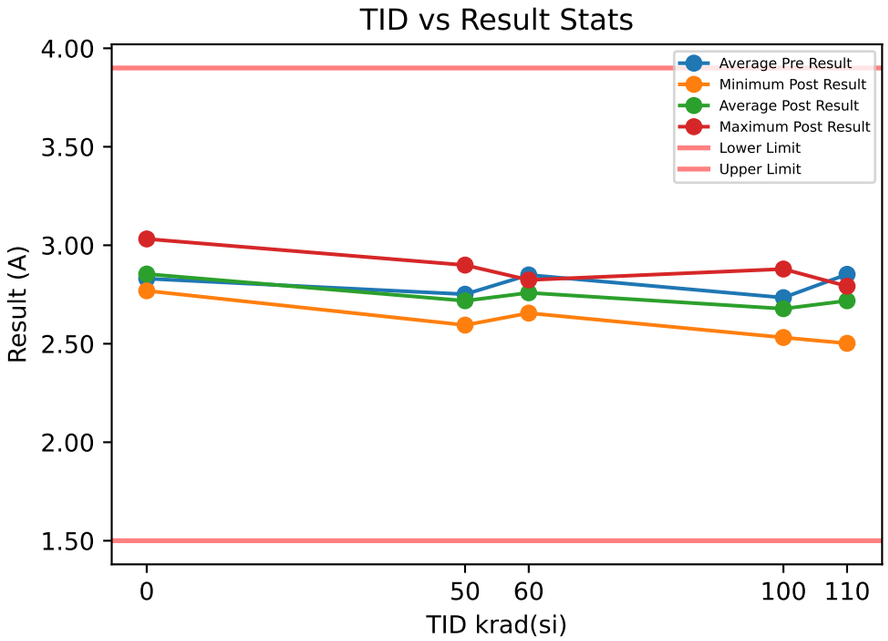
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

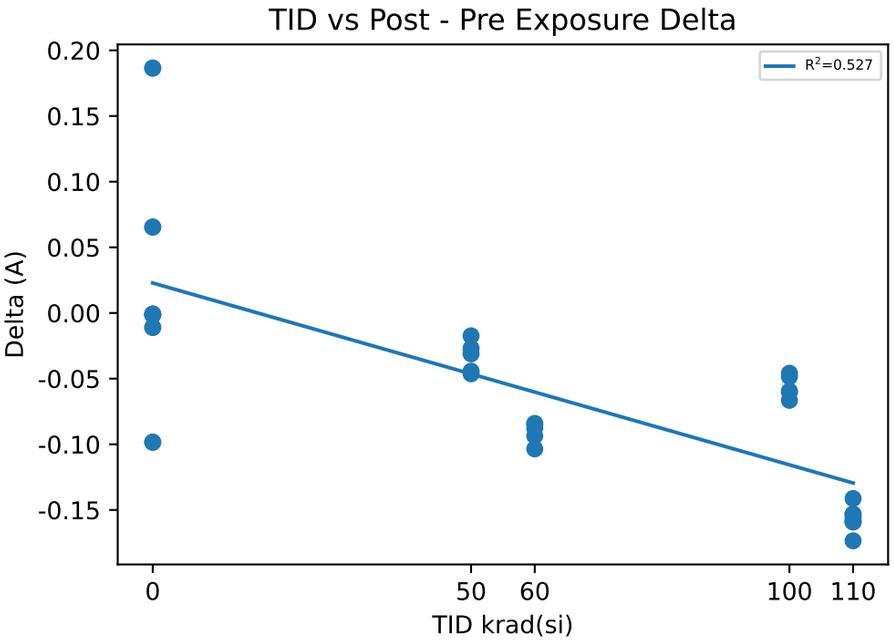
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.7171	2.7167	-0.0004
2	0	CU2	2.8795	2.876	-0.0035
3	0	CU3	2.6619	2.6563	-0.0056
11	50	Unbiased-50k	2.6784	2.6555	-0.0229
12	50	Unbiased-50k	2.7768	2.7519	-0.0249
13	50	Unbiased-50k	2.8198	2.7958	-0.024
14	50	Unbiased-50k	2.7965	2.7721	-0.0244
16	50	Unbiased-50k	2.8554	2.8258	-0.0296
17	60	Biased-50k	2.9454	2.861	-0.0844
18	60	Biased-50k	2.7618	2.663	-0.0988
19	60	Biased-50k	2.8068	2.7223	-0.0845
20	60	Biased-50k	2.7278	2.6338	-0.094
21	60	Biased-50k	2.6445	2.5559	-0.0886
24	100	Unbiased-100k	2.7827	2.7278	-0.0549
25	100	Unbiased-100k	2.6729	2.626	-0.0469
26	100	Unbiased-100k	2.5888	2.5574	-0.0314
27	100	Unbiased-100k	2.575	2.5282	-0.0468
28	100	Unbiased-100k	2.6334	2.5925	-0.0409
29	110	Biased-100k	2.7626	2.6181	-0.1445
30	110	Biased-100k	2.8341	2.6951	-0.139
31	110	Biased-100k	2.7886	2.6237	-0.1649
32	110	Biased-100k	2.9245	2.6813	-0.2432
34	110	Biased-100k	2.7116	2.572	-0.1396

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6619	2.7528	2.8795	0.11312	2.6563	2.7497	2.876	0.1135	-0.0056	-0.0031667	-0.0004	0.002616
50	2.6784	2.7854	2.8554	0.066576	2.6555	2.7602	2.8258	0.064698	-0.0296	-0.02516	-0.0229	0.002589
60	2.6445	2.7773	2.9454	0.11119	2.5559	2.6872	2.861	0.11414	-0.0988	-0.09006	-0.0844	0.0062648
100	2.575	2.6506	2.7827	0.083334	2.5282	2.6064	2.7278	0.077187	-0.0549	-0.04418	-0.0314	0.0087073
110	2.7116	2.8043	2.9245	0.08049	2.572	2.638	2.6951	0.050229	-0.2432	-0.16624	-0.139	0.044297

Device Test: 28.7 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW2/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK)





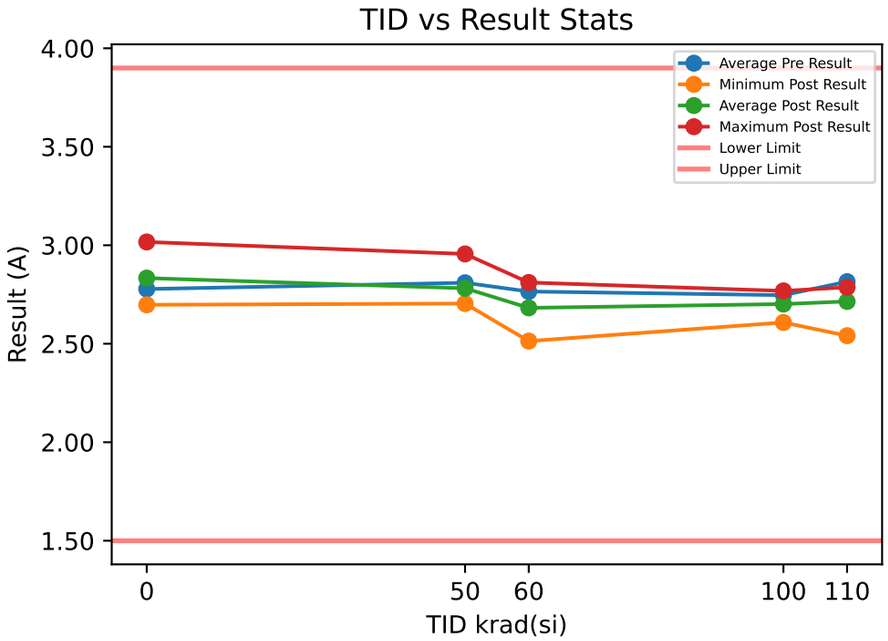
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

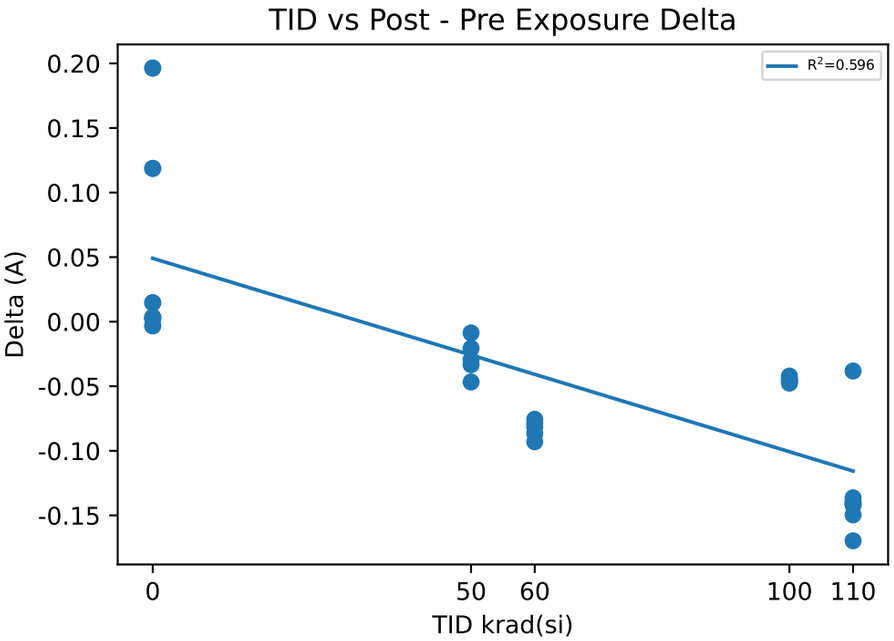
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.8455	2.844	-0.0015
2	0	CU2	2.7788	2.778	-0.0008
3	0	CU3	2.8672	2.8562	-0.011
11	50	Unbiased-50k	2.6216	2.5947	-0.0269
12	50	Unbiased-50k	2.7788	2.7325	-0.0463
13	50	Unbiased-50k	2.7219	2.6776	-0.0443
14	50	Unbiased-50k	2.9304	2.8993	-0.0311
16	50	Unbiased-50k	2.7041	2.6867	-0.0174
17	60	Biased-50k	2.7401	2.6555	-0.0846
18	60	Biased-50k	2.9174	2.8238	-0.0936
19	60	Biased-50k	2.9257	2.8222	-0.1035
20	60	Biased-50k	2.883	2.7989	-0.0841
21	60	Biased-50k	2.7803	2.6926	-0.0877
24	100	Unbiased-100k	2.654	2.5945	-0.0595
25	100	Unbiased-100k	2.6457	2.5972	-0.0485
26	100	Unbiased-100k	2.8325	2.7866	-0.0459
27	100	Unbiased-100k	2.592	2.5317	-0.0603
28	100	Unbiased-100k	2.9458	2.8793	-0.0665
29	110	Biased-100k	2.8376	2.6963	-0.1413
30	110	Biased-100k	2.8893	2.731	-0.1583
31	110	Biased-100k	2.6575	2.5021	-0.1554
32	110	Biased-100k	2.9656	2.7921	-0.1735
34	110	Biased-100k	2.9122	2.759	-0.1532

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7788	2.8305	2.8672	0.046069	2.778	2.8261	2.8562	0.042072	-0.011	-0.0044333	-0.0008	0.0056977
50	2.6216	2.7514	2.9304	0.11483	2.5947	2.7182	2.8993	0.1128	-0.0463	-0.0332	-0.0174	0.01213
60	2.7401	2.8493	2.9257	0.084107	2.6555	2.7586	2.8238	0.078908	-0.1035	-0.0907	-0.0841	0.0080935
100	2.592	2.734	2.9458	0.1491	2.5317	2.6779	2.8793	0.14767	-0.0665	-0.05614	-0.0459	0.008648
110	2.6575	2.8524	2.9656	0.11828	2.5021	2.6961	2.7921	0.11405	-0.1735	-0.15634	-0.1413	0.011568

Device Test: 28.8 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW3/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK)





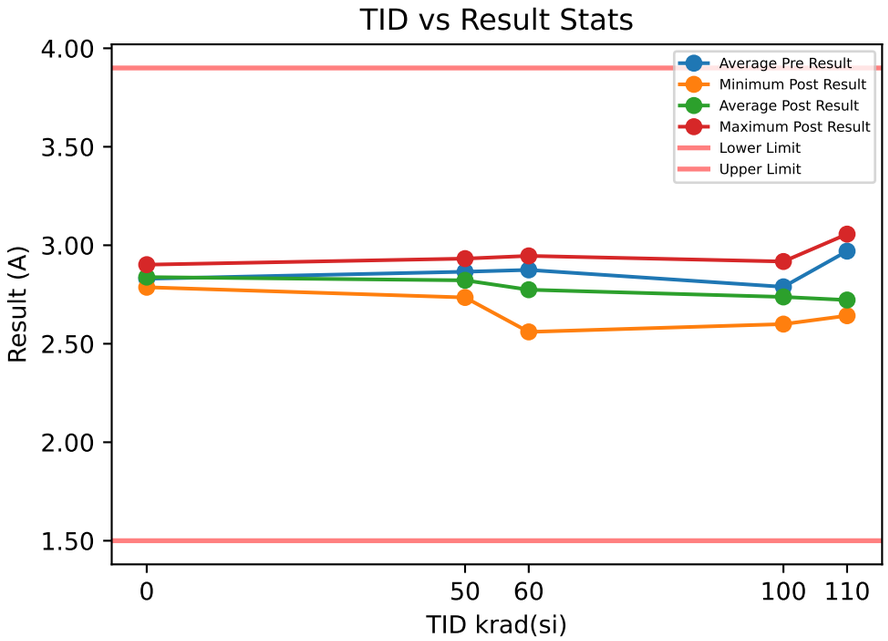
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

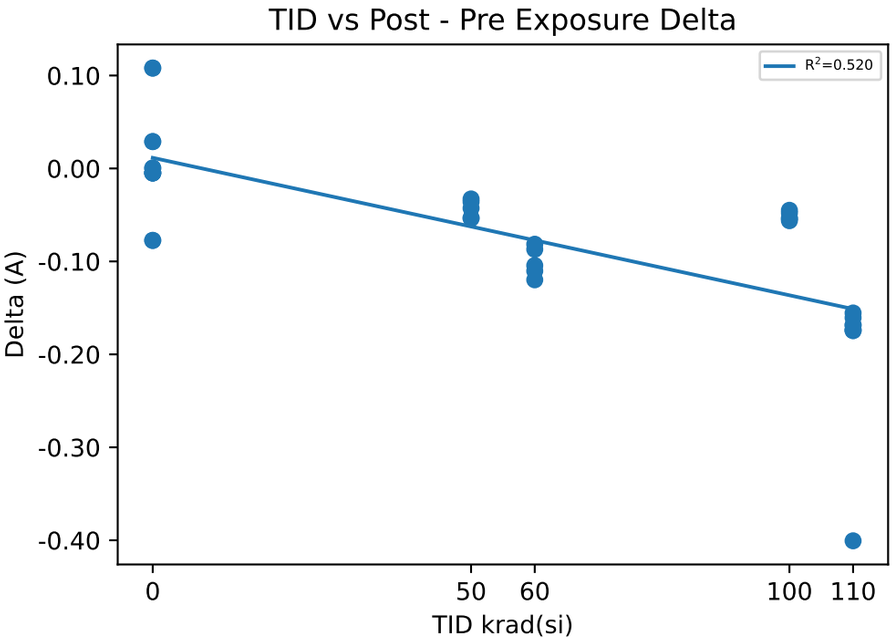
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.8203	2.8171	-0.0032
2	0	CU2	2.8191	2.8215	0.0024
3	0	CU3	2.6942	2.6977	0.0035
11	50	Unbiased-50k	2.7333	2.704	-0.0293
12	50	Unbiased-50k	2.7997	2.753	-0.0467
13	50	Unbiased-50k	2.7946	2.774	-0.0206
14	50	Unbiased-50k	2.9646	2.9559	-0.0087
16	50	Unbiased-50k	2.7547	2.7214	-0.0333
17	60	Biased-50k	2.7563	2.6775	-0.0788
18	60	Biased-50k	2.7531	2.6716	-0.0815
19	60	Biased-50k	2.8974	2.8108	-0.0866
20	60	Biased-50k	2.8302	2.7372	-0.093
21	60	Biased-50k	2.589	2.5134	-0.0756
24	100	Unbiased-100k	2.6535	2.608	-0.0455
25	100	Unbiased-100k	2.8017	2.7541	-0.0476
26	100	Unbiased-100k	2.7428	2.6964	-0.0464
27	100	Unbiased-100k	2.7246	2.6802	-0.0444
28	100	Unbiased-100k	2.8104	2.7683	-0.0421
29	110	Biased-100k	2.8132	2.6435	-0.1697
30	110	Biased-100k	2.8606	2.711	-0.1496
31	110	Biased-100k	2.6772	2.5408	-0.1364
32	110	Biased-100k	2.825	2.7868	-0.0382
34	110	Biased-100k	2.8998	2.7596	-0.1402

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6942	2.7779	2.8203	0.07246	2.6977	2.7788	2.8215	0.07024	-0.0032	0.0009	0.0035	0.003593
50	2.7333	2.8094	2.9646	0.091082	2.704	2.7817	2.9559	0.10112	-0.0467	-0.02772	-0.0087	0.014198
60	2.589	2.7652	2.8974	0.11508	2.5134	2.6821	2.8108	0.10976	-0.093	-0.0831	-0.0756	0.0068476
100	2.6535	2.7466	2.8104	0.063782	2.608	2.7014	2.7683	0.064131	-0.0476	-0.0452	-0.0421	0.002094
110	2.6772	2.8152	2.8998	0.084206	2.5408	2.6883	2.7868	0.098824	-0.1697	-0.12682	-0.0382	0.051191

Device Test: 28.9 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW4/3/3///90.9/634//1.8///@LOW_SIDE_OC_SINK)





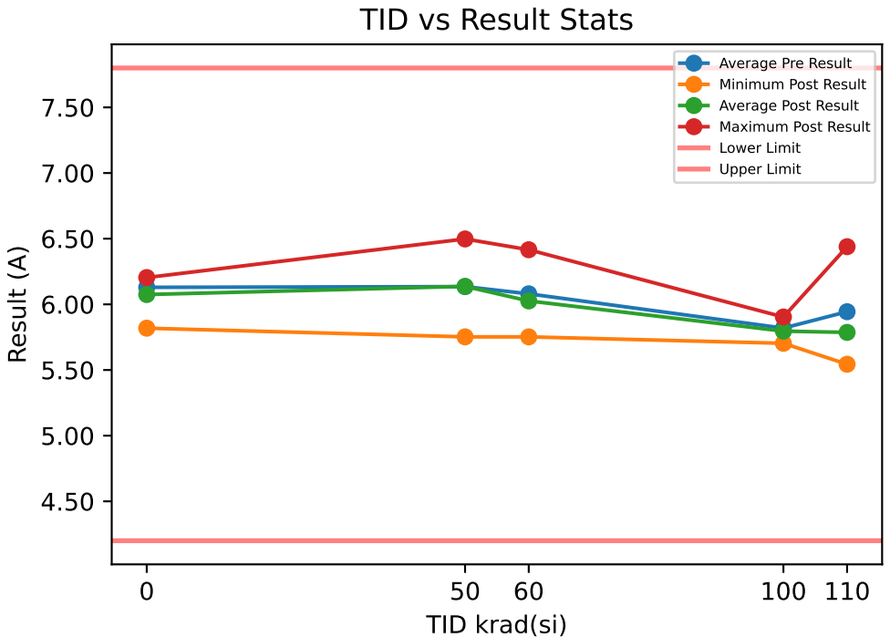
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

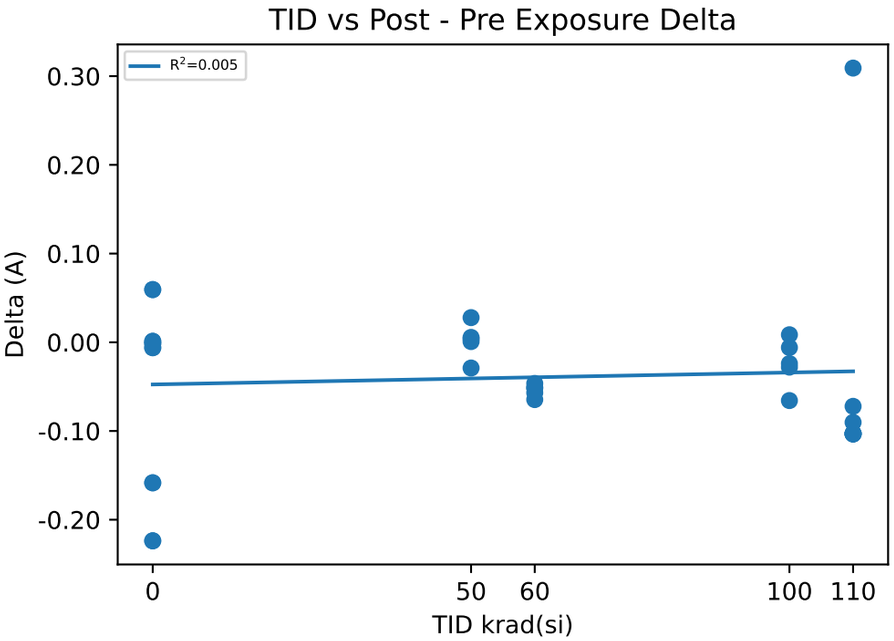
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.7934	2.7886	-0.0048
2	0	CU2	2.8642	2.8646	0.0004
3	0	CU3	2.8322	2.8274	-0.0048
11	50	Unbiased-50k	2.7677	2.7349	-0.0328
12	50	Unbiased-50k	2.8175	2.7637	-0.0538
13	50	Unbiased-50k	2.9005	2.8475	-0.053
14	50	Unbiased-50k	2.8741	2.8313	-0.0428
16	50	Unbiased-50k	2.9681	2.9322	-0.0359
17	60	Biased-50k	2.9377	2.8507	-0.087
18	60	Biased-50k	3.0658	2.946	-0.1198
19	60	Biased-50k	3.0357	2.9254	-0.1103
20	60	Biased-50k	2.693	2.5886	-0.1044
21	60	Biased-50k	2.6416	2.5601	-0.0815
24	100	Unbiased-100k	2.9654	2.9175	-0.0479
25	100	Unbiased-100k	2.8705	2.8255	-0.045
26	100	Unbiased-100k	2.7661	2.7122	-0.0539
27	100	Unbiased-100k	2.6867	2.6332	-0.0535
28	100	Unbiased-100k	2.6559	2.5997	-0.0562
29	110	Biased-100k	2.8029	2.6423	-0.1606
30	110	Biased-100k	3.2298	3.0565	-0.1733
31	110	Biased-100k	2.8934	2.7379	-0.1555
32	110	Biased-100k	3.0907	2.6901	-0.4006
34	110	Biased-100k	2.8337	2.6593	-0.1744

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.7934	2.8299	2.8642	0.035454	2.7886	2.8269	2.8646	0.038003	-0.0048	-0.0030667	0.0004	0.0030022
50	2.7677	2.8656	2.9681	0.076965	2.7349	2.8219	2.9322	0.077243	-0.0538	-0.04366	-0.0328	0.0096041
60	2.6416	2.8748	3.0658	0.19606	2.5601	2.7742	2.946	0.18609	-0.1198	-0.1006	-0.0815	0.016023
100	2.6559	2.7889	2.9654	0.1289	2.5997	2.7376	2.9175	0.1329	-0.0562	-0.0513	-0.045	0.0046599
110	2.8029	2.9701	3.2298	0.18332	2.6423	2.7572	3.0565	0.1712	-0.4006	-0.21288	-0.1555	0.10525

Device Test: 29.2 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW1/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





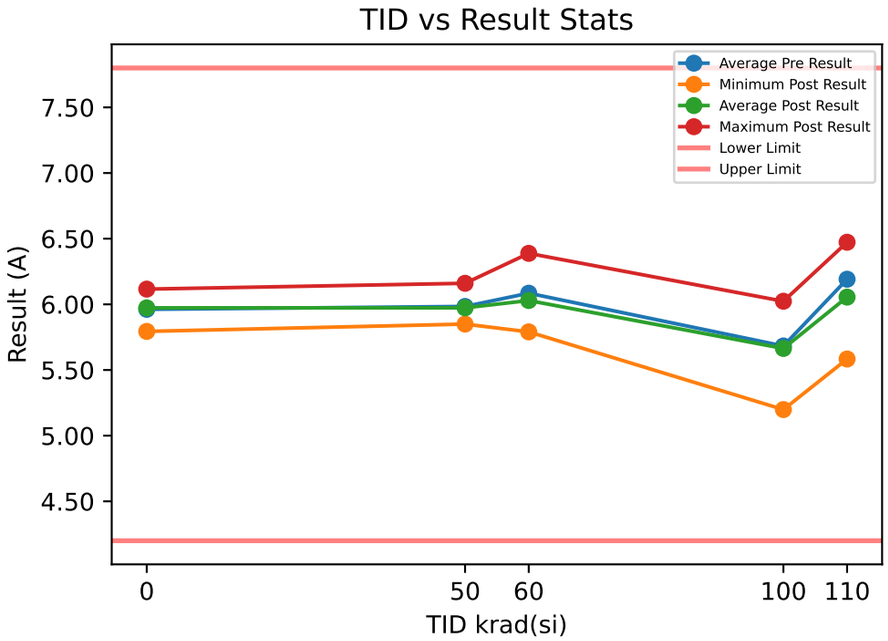
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

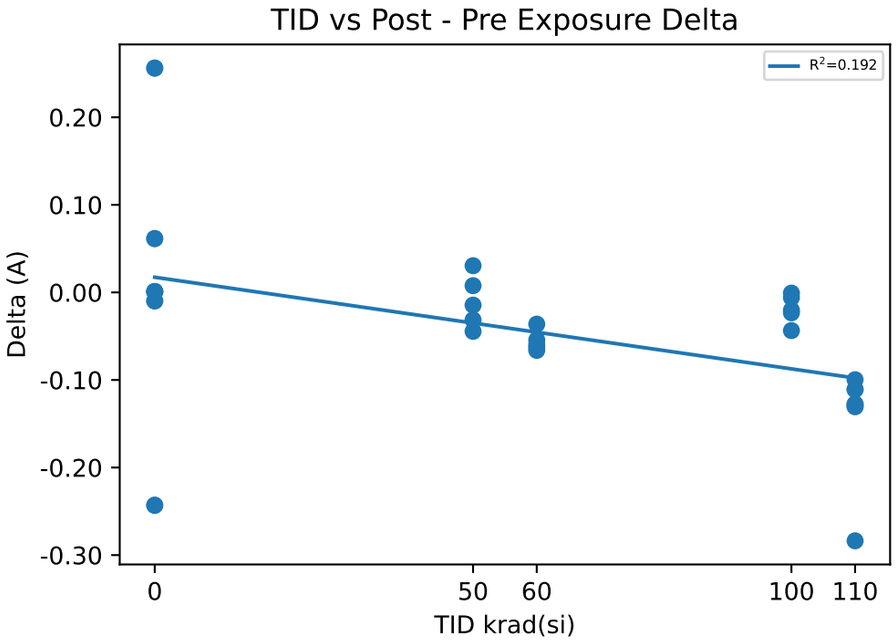
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0423	6.0409	-0.0014
2	0	CU2	6.2018	6.2029	0.0011
3	0	CU3	6.1446	6.1385	-0.0061
11	50	Unbiased-50k	5.7516	5.7524	0.0008
12	50	Unbiased-50k	6.0245	6.0523	0.0278
13	50	Unbiased-50k	6.1446	6.1156	-0.029
14	50	Unbiased-50k	6.4925	6.498	0.0055
16	50	Unbiased-50k	6.2619	6.2657	0.0038
17	60	Biased-50k	6.4672	6.4158	-0.0514
18	60	Biased-50k	6.0423	5.9777	-0.0646
19	60	Biased-50k	6.1347	6.0883	-0.0464
20	60	Biased-50k	5.9471	5.8959	-0.0512
21	60	Biased-50k	5.8093	5.7524	-0.0569
24	100	Unbiased-100k	5.8717	5.8437	-0.028
25	100	Unbiased-100k	5.9096	5.9037	-0.0059
26	100	Unbiased-100k	5.6975	5.706	0.0085
27	100	Unbiased-100k	5.8472	5.8232	-0.024
28	100	Unbiased-100k	5.769	5.7033	-0.0657
29	110	Biased-100k	5.624	5.5518	-0.0722
30	110	Biased-100k	6.2619	6.1716	-0.0903
31	110	Biased-100k	6.0569	5.9534	-0.1035
32	110	Biased-100k	6.13	6.4391	0.3091
34	110	Biased-100k	5.6469	5.5439	-0.103

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0423	6.1296	6.2018	0.080806	6.0409	6.1274	6.2029	0.081565	-0.0061	-0.0021333	0.0011	0.0036556
50	5.7516	6.135	6.4925	0.27532	5.7524	6.1368	6.498	0.27497	-0.029	0.00178	0.0278	0.020269
60	5.8093	6.0801	6.4672	0.24763	5.7524	6.026	6.4158	0.24997	-0.0646	-0.0541	-0.0464	0.0069477
100	5.6975	5.819	5.9096	0.08521	5.7033	5.796	5.9037	0.08847	-0.0657	-0.02302	0.0085	0.027991
110	5.624	5.9439	6.2619	0.29115	5.5439	5.932	6.4391	0.39057	-0.1035	-0.01198	0.3091	0.17994

Device Test: 29.3 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW2/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





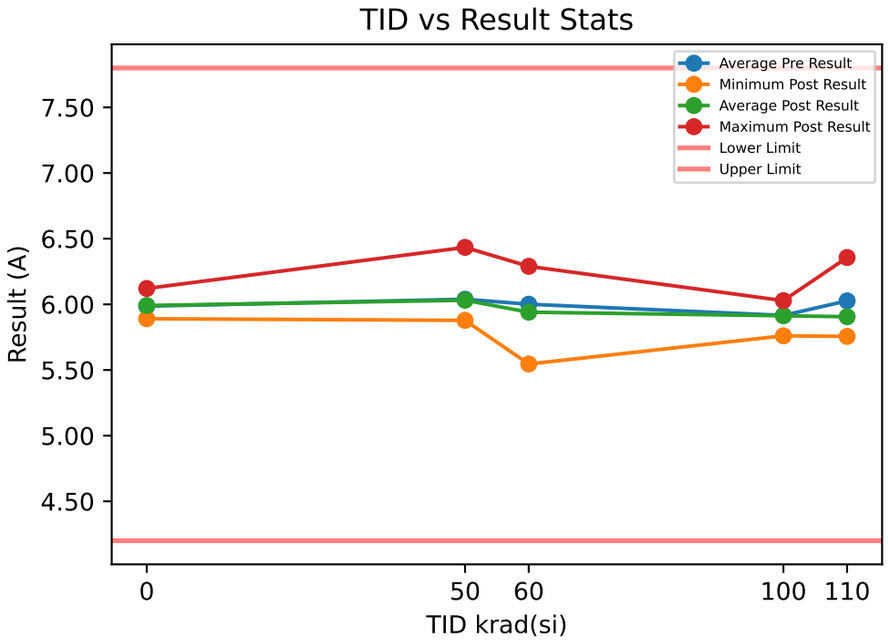
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

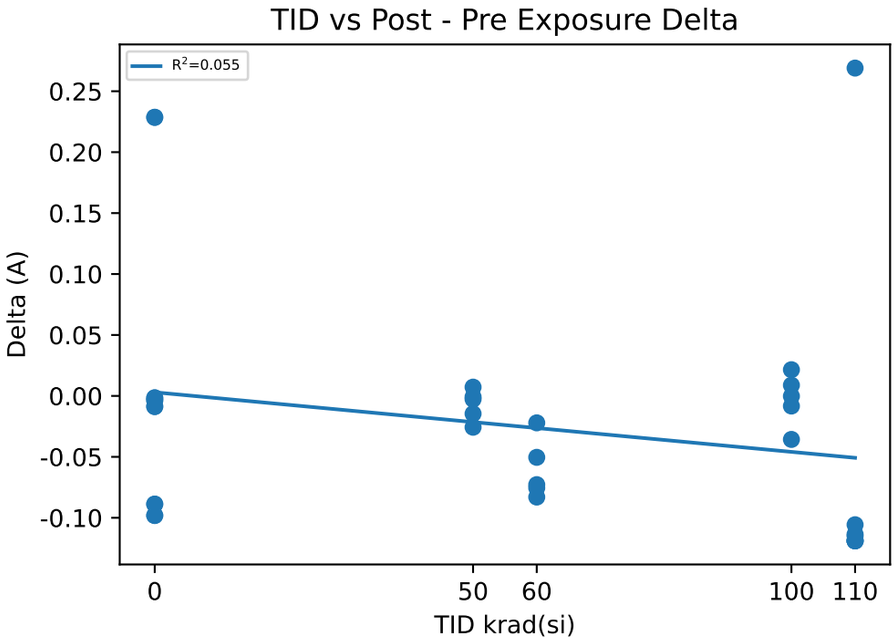
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0545	6.0555	0.001
2	0	CU2	5.7947	5.7955	0.0008
3	0	CU3	6.0371	6.0274	-0.0097
11	50	Unbiased-50k	5.8191	5.8496	0.0305
12	50	Unbiased-50k	5.9495	5.905	-0.0445
13	50	Unbiased-50k	6.1244	6.093	-0.0314
14	50	Unbiased-50k	6.1525	6.1602	0.0077
16	50	Unbiased-50k	5.8744	5.8599	-0.0145
17	60	Biased-50k	6.1118	6.0456	-0.0662
18	60	Biased-50k	6.0541	5.9911	-0.063
19	60	Biased-50k	6.4424	6.3882	-0.0542
20	60	Biased-50k	5.9898	5.9302	-0.0596
21	60	Biased-50k	5.8266	5.7904	-0.0362
24	100	Unbiased-100k	5.6118	5.611	-0.0008
25	100	Unbiased-100k	5.7394	5.7191	-0.0203
26	100	Unbiased-100k	6.047	6.0237	-0.0233
27	100	Unbiased-100k	5.2046	5.1987	-0.0059
28	100	Unbiased-100k	5.812	5.7684	-0.0436
29	110	Biased-100k	6.1647	6.054	-0.1107
30	110	Biased-100k	6.5727	6.473	-0.0997
31	110	Biased-100k	5.6947	5.5837	-0.111
32	110	Biased-100k	6.3227	6.039	-0.2837
34	110	Biased-100k	6.2018	6.0742	-0.1276

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7947	5.9621	6.0545	0.14523	5.7955	5.9595	6.0555	0.14269	-0.0097	-0.0026333	0.001	0.0061207
50	5.8191	5.984	6.1525	0.14874	5.8496	5.9735	6.1602	0.14325	-0.0445	-0.01044	0.0305	0.030088
60	5.8266	6.0849	6.4424	0.22652	5.7904	6.0291	6.3882	0.22216	-0.0662	-0.05584	-0.0362	0.011844
100	5.2046	5.683	6.047	0.31075	5.1987	5.6642	6.0237	0.30109	-0.0436	-0.01878	-0.0008	0.016792
110	5.6947	6.1913	6.5727	0.32022	5.5837	6.0448	6.473	0.31502	-0.2837	-0.14654	-0.0997	0.077319

Device Test: 29.4 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW3/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





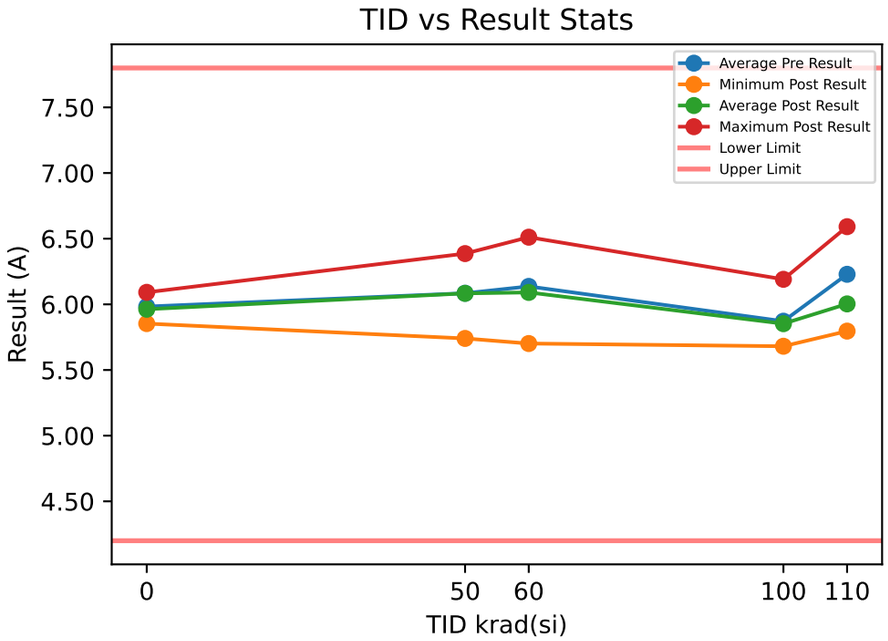
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

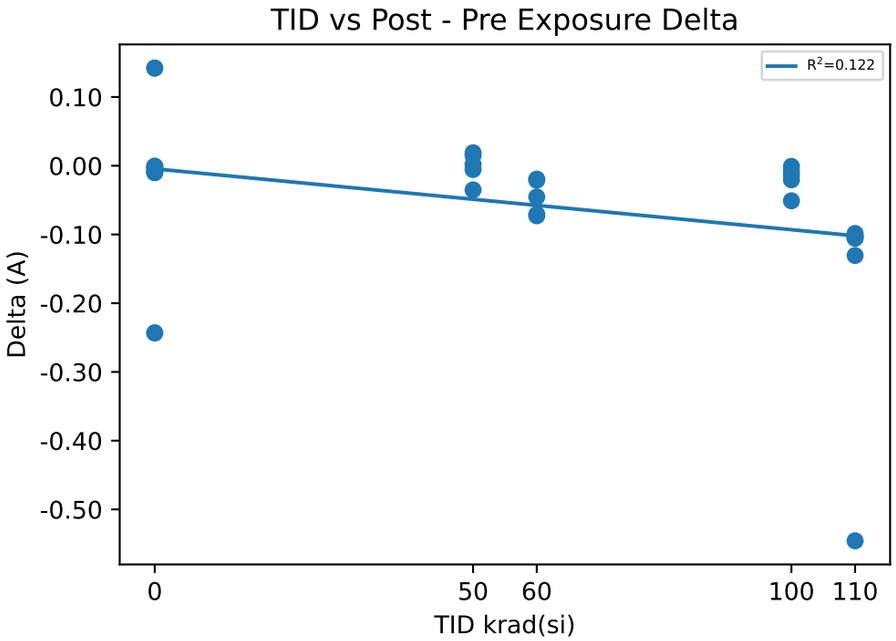
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8922	5.8906	-0.0016
2	0	CU2	5.9895	5.9859	-0.0036
3	0	CU3	6.0769	6.0682	-0.0087
11	50	Unbiased-50k	5.9116	5.897	-0.0146
12	50	Unbiased-50k	5.9037	5.878	-0.0257
13	50	Unbiased-50k	5.897	5.8962	-0.0008
14	50	Unbiased-50k	6.4267	6.4339	0.0072
16	50	Unbiased-50k	6.0543	6.0516	-0.0027
17	60	Biased-50k	6.0666	5.9911	-0.0755
18	60	Biased-50k	6.0796	5.9966	-0.083
19	60	Biased-50k	6.3117	6.2896	-0.0221
20	60	Biased-50k	5.9512	5.8784	-0.0728
21	60	Biased-50k	5.5962	5.5458	-0.0504
24	100	Unbiased-100k	5.9816	5.9459	-0.0357
25	100	Unbiased-100k	6.0286	6.0284	-0.0002
26	100	Unbiased-100k	5.7515	5.7603	0.0088
27	100	Unbiased-100k	5.8337	5.8254	-0.0083
28	100	Unbiased-100k	5.9844	6.0059	0.0215
29	110	Biased-100k	5.929	5.8155	-0.1135
30	110	Biased-100k	6.3615	6.2558	-0.1057
31	110	Biased-100k	5.8709	5.7559	-0.115
32	110	Biased-100k	6.0875	6.3565	0.269
34	110	Biased-100k	5.8843	5.7654	-0.1189

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8922	5.9862	6.0769	0.092394	5.8906	5.9816	6.0682	0.088879	-0.0087	-0.0046333	-0.0016	0.0036611
50	5.897	6.0387	6.4267	0.22652	5.878	6.0313	6.4339	0.23574	-0.0257	-0.00732	0.0072	0.012899
60	5.5962	6.0011	6.3117	0.26142	5.5458	5.9403	6.2896	0.26797	-0.083	-0.06076	-0.0221	0.024793
100	5.7515	5.916	6.0286	0.11779	5.7603	5.9132	6.0284	0.11621	-0.0357	-0.00278	0.0215	0.021474
110	5.8709	6.0266	6.3615	0.20609	5.7559	5.9898	6.3565	0.29183	-0.1189	-0.03682	0.269	0.17103

Device Test: 29.5 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW4/7/7///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





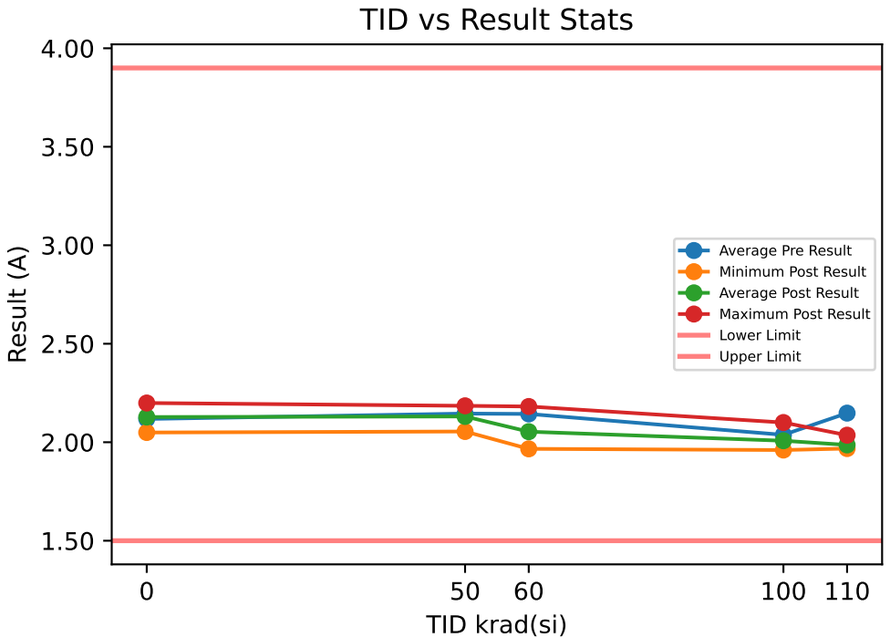
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

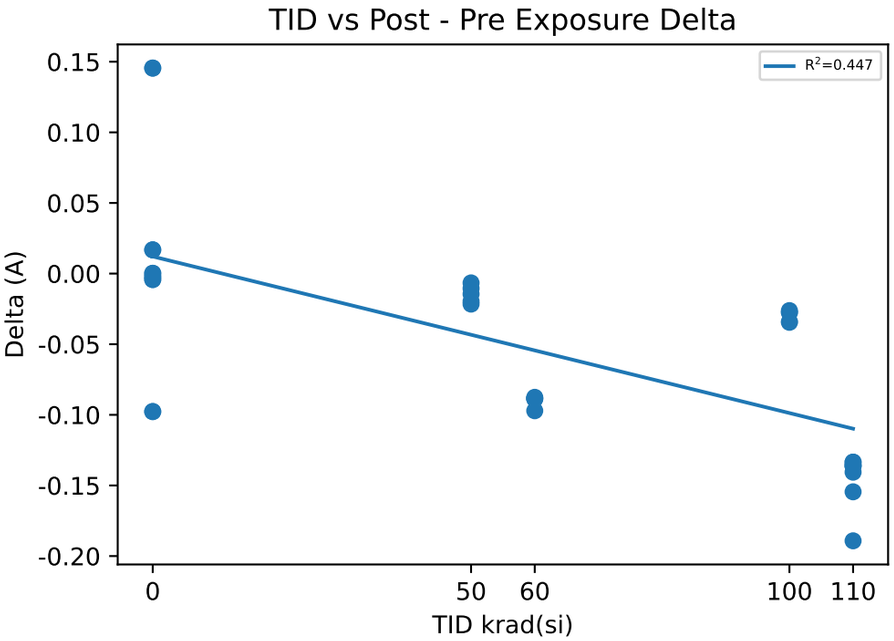
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9942	5.9934	-0.0008
2	0	CU2	5.8563	5.8535	-0.0028
3	0	CU3	6.099	6.0915	-0.0075
11	50	Unbiased-50k	5.7215	5.7404	0.0189
12	50	Unbiased-50k	5.8689	5.8634	-0.0055
13	50	Unbiased-50k	6.3844	6.3865	0.0021
14	50	Unbiased-50k	6.3267	6.3414	0.0147
16	50	Unbiased-50k	6.1215	6.0864	-0.0351
17	60	Biased-50k	6.0093	5.9883	-0.021
18	60	Biased-50k	6.3219	6.2512	-0.0707
19	60	Biased-50k	6.5568	6.5114	-0.0454
20	60	Biased-50k	6.0741	6.0013	-0.0728
21	60	Biased-50k	5.7211	5.7016	-0.0195
24	100	Unbiased-100k	6.199	6.1907	-0.0083
25	100	Unbiased-100k	5.6946	5.6809	-0.0137
26	100	Unbiased-100k	5.8417	5.8408	-0.0009
27	100	Unbiased-100k	5.759	5.7385	-0.0205
28	100	Unbiased-100k	5.8638	5.8128	-0.051
29	110	Biased-100k	6.0591	5.9285	-0.1306
30	110	Biased-100k	6.69	6.5915	-0.0985
31	110	Biased-100k	5.897	5.7962	-0.1008
32	110	Biased-100k	6.4394	5.8937	-0.5457
34	110	Biased-100k	6.0587	5.9553	-0.1034

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8563	5.9832	6.099	0.12173	5.8535	5.9795	6.0915	0.11961	-0.0075	-0.0037	-0.0008	0.0034395
50	5.7215	6.0846	6.3844	0.28645	5.7404	6.0836	6.3865	0.28482	-0.0351	-0.00098	0.0189	0.021419
60	5.7211	6.1366	6.5568	0.31767	5.7016	6.0908	6.5114	0.30522	-0.0728	-0.04588	-0.0195	0.025768
100	5.6946	5.8716	6.199	0.19503	5.6809	5.8527	6.1907	0.19908	-0.051	-0.01888	-0.0009	0.019341
110	5.897	6.2288	6.69	0.32591	5.7962	6.033	6.5915	0.31795	-0.5457	-0.1958	-0.0985	0.19603

Device Test: 29.6 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW1/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK)





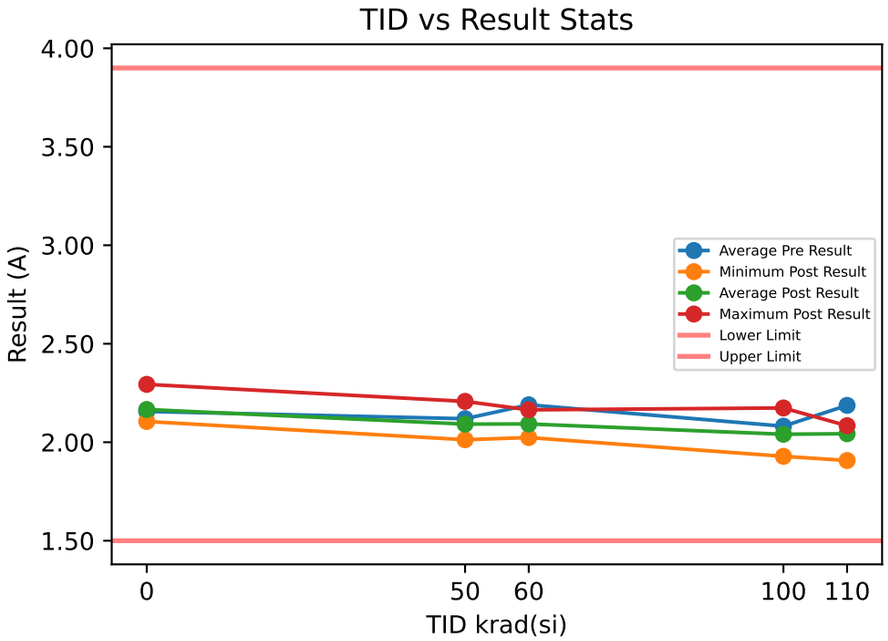
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

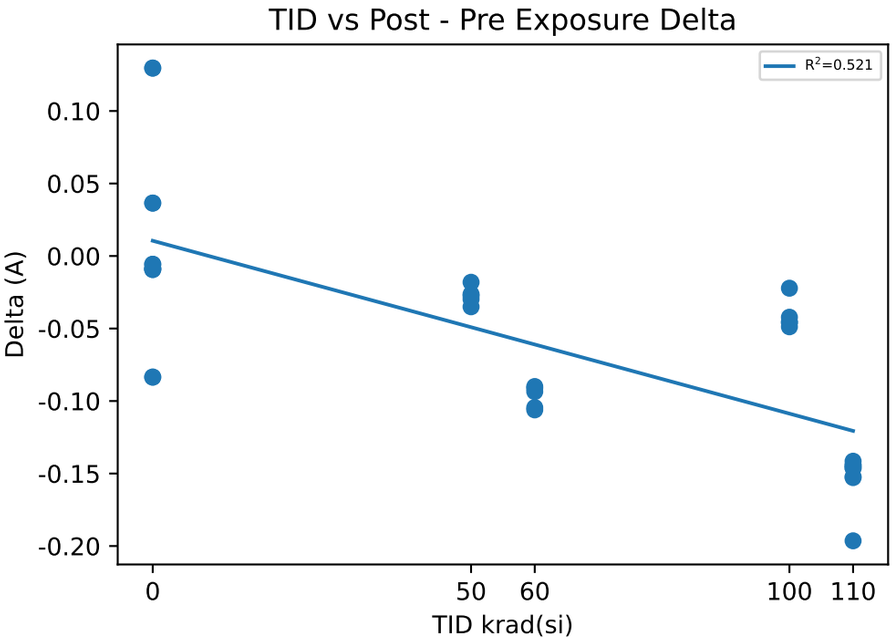
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1014	2.1016	0.0002
2	0	CU2	2.1994	2.1972	-0.0022
3	0	CU3	2.0536	2.0494	-0.0042
11	50	Unbiased-50k	2.069	2.0545	-0.0145
12	50	Unbiased-50k	2.1334	2.1229	-0.0105
13	50	Unbiased-50k	2.154	2.1474	-0.0066
14	50	Unbiased-50k	2.1642	2.1446	-0.0196
16	50	Unbiased-50k	2.2065	2.1849	-0.0216
17	60	Biased-50k	2.2697	2.1814	-0.0883
18	60	Biased-50k	2.1295	2.0324	-0.0971
19	60	Biased-50k	2.1623	2.0739	-0.0884
20	60	Biased-50k	2.1026	2.0138	-0.0888
21	60	Biased-50k	2.054	1.9664	-0.0876
24	100	Unbiased-100k	2.1346	2.1001	-0.0345
25	100	Unbiased-100k	2.0355	2.0093	-0.0262
26	100	Unbiased-100k	1.9905	1.9632	-0.0273
27	100	Unbiased-100k	1.9944	1.9604	-0.034
28	100	Unbiased-100k	2.0327	2.005	-0.0277
29	110	Biased-100k	2.1247	1.9841	-0.1406
30	110	Biased-100k	2.163	2.0267	-0.1363
31	110	Biased-100k	2.1224	1.9679	-0.1545
32	110	Biased-100k	2.225	2.0358	-0.1892
34	110	Biased-100k	2.1038	1.9679	-0.1359

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0536	2.1181	2.1994	0.074326	2.0494	2.1161	2.1972	0.074954	-0.0042	-0.0020667	0.0002	0.002203
50	2.069	2.1454	2.2065	0.050353	2.0545	2.1309	2.1849	0.048158	-0.0216	-0.01456	-0.0066	0.0062212
60	2.054	2.1436	2.2697	0.080869	1.9664	2.0536	2.1814	0.081213	-0.0971	-0.09004	-0.0876	0.0039703
100	1.9905	2.0375	2.1346	0.058142	1.9604	2.0076	2.1001	0.056491	-0.0345	-0.02994	-0.0262	0.0039766
110	2.1038	2.1478	2.225	0.048233	1.9679	1.9965	2.0358	0.032581	-0.1892	-0.1513	-0.1359	0.022491

Device Test: 29.7 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW2/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK)





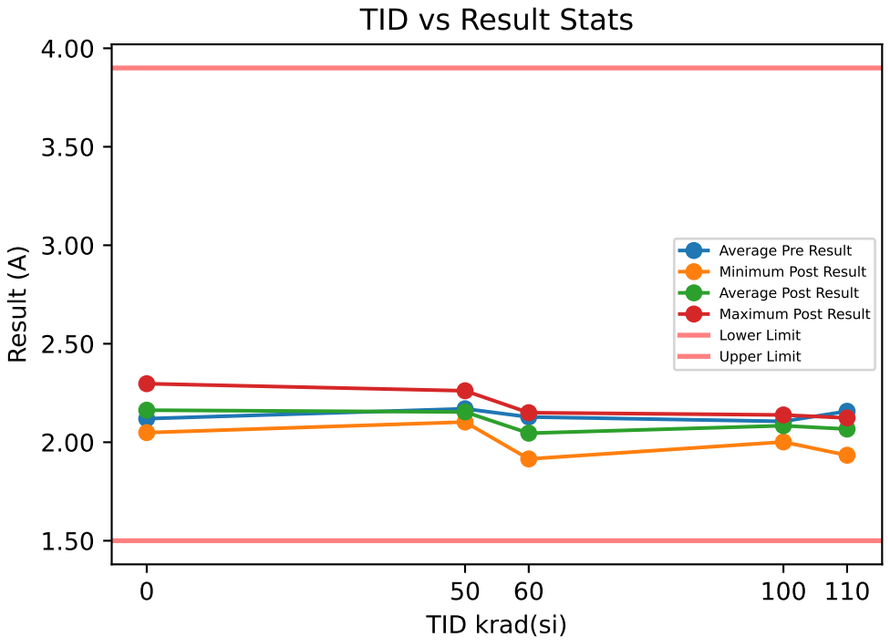
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

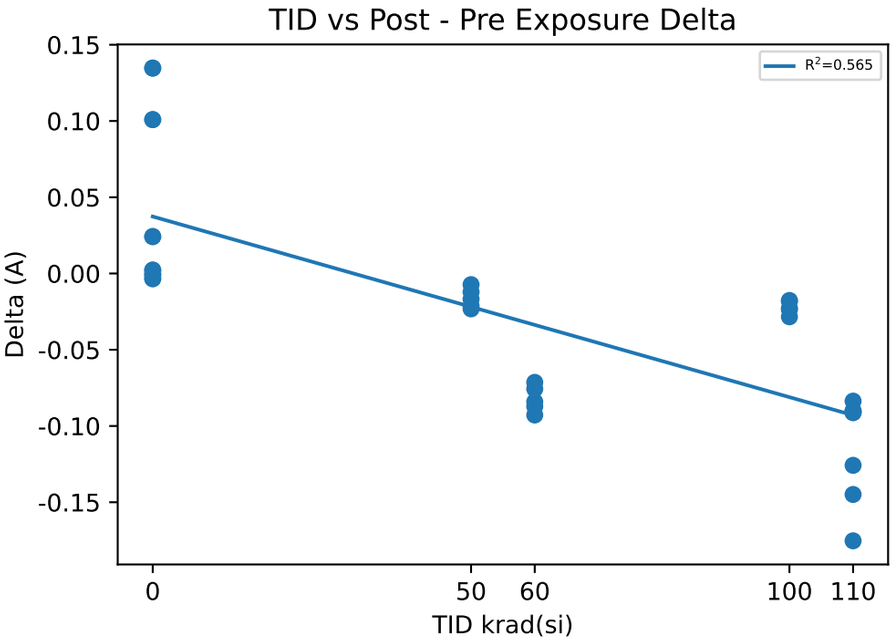
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1642	2.1585	-0.0057
2	0	CU2	2.1141	2.1055	-0.0086
3	0	CU3	2.1907	2.1814	-0.0093
11	50	Unbiased-50k	2.0402	2.0127	-0.0275
12	50	Unbiased-50k	2.1393	2.1095	-0.0298
13	50	Unbiased-50k	2.0931	2.0581	-0.035
14	50	Unbiased-50k	2.2337	2.2074	-0.0263
16	50	Unbiased-50k	2.0904	2.0723	-0.0181
17	60	Biased-50k	2.1149	2.0237	-0.0912
18	60	Biased-50k	2.2689	2.1644	-0.1045
19	60	Biased-50k	2.2385	2.1324	-0.1061
20	60	Biased-50k	2.2124	2.1189	-0.0935
21	60	Biased-50k	2.1149	2.0249	-0.09
24	100	Unbiased-100k	2.0181	1.9723	-0.0458
25	100	Unbiased-100k	2.0315	2.0093	-0.0222
26	100	Unbiased-100k	2.1642	2.1186	-0.0456
27	100	Unbiased-100k	1.9707	1.9285	-0.0422
28	100	Unbiased-100k	2.2227	2.1739	-0.0488
29	110	Biased-100k	2.1761	2.0239	-0.1522
30	110	Biased-100k	2.2077	2.0662	-0.1415
31	110	Biased-100k	2.06	1.9072	-0.1528
32	110	Biased-100k	2.2803	2.0839	-0.1964
34	110	Biased-100k	2.2112	2.065	-0.1462

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1141	2.1563	2.1907	0.038901	2.1055	2.1485	2.1814	0.038932	-0.0093	-0.0078667	-0.0057	0.0019088
50	2.0402	2.1193	2.2337	0.072914	2.0127	2.092	2.2074	0.073228	-0.035	-0.02734	-0.0181	0.0061484
60	2.1149	2.1899	2.2689	0.071343	2.0237	2.0929	2.1644	0.064732	-0.1061	-0.09706	-0.09	0.0076474
100	1.9707	2.0814	2.2227	0.10674	1.9285	2.0405	2.1739	0.10255	-0.0488	-0.04092	-0.0222	0.010722
110	2.06	2.1871	2.2803	0.080571	1.9072	2.0292	2.0839	0.071685	-0.1964	-0.15782	-0.1415	0.02206

Device Test: 29.8 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW3/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK)





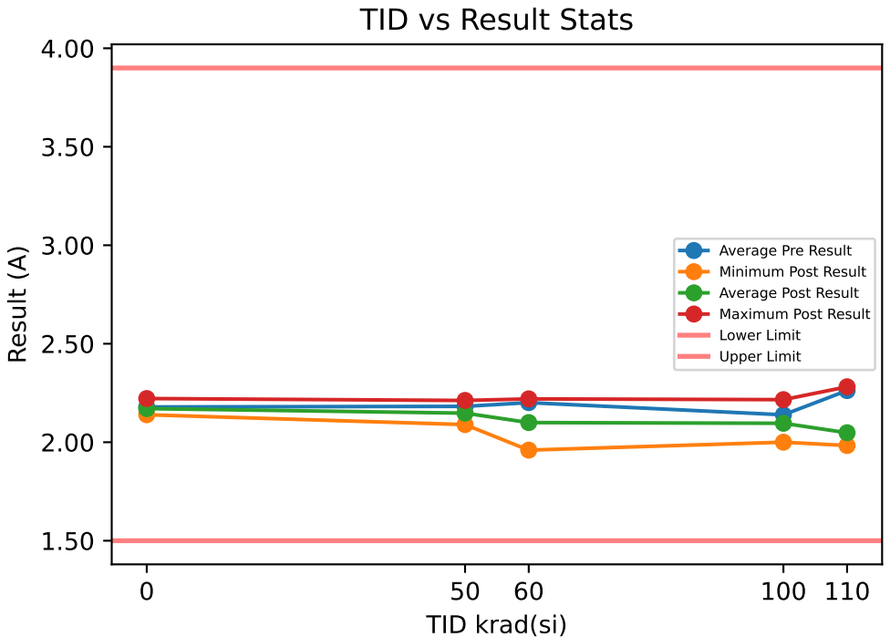
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

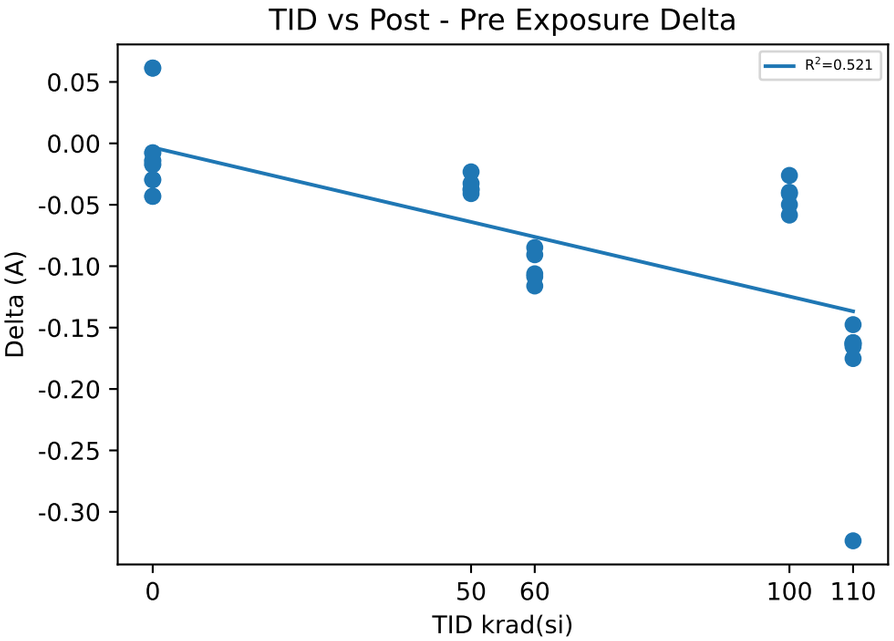
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1625	2.1619	-0.0006
2	0	CU2	2.1443	2.1465	0.0022
3	0	CU3	2.0522	2.0488	-0.0034
11	50	Unbiased-50k	2.1194	2.1026	-0.0168
12	50	Unbiased-50k	2.1649	2.1528	-0.0121
13	50	Unbiased-50k	2.1653	2.1441	-0.0212
14	50	Unbiased-50k	2.2685	2.2612	-0.0073
16	50	Unbiased-50k	2.1313	2.1081	-0.0232
17	60	Biased-50k	2.1226	2.0512	-0.0714
18	60	Biased-50k	2.123	2.0389	-0.0841
19	60	Biased-50k	2.2372	2.15	-0.0872
20	60	Biased-50k	2.1669	2.0741	-0.0928
21	60	Biased-50k	1.9909	1.9152	-0.0757
24	100	Unbiased-100k	2.0242	2.0014	-0.0228
25	100	Unbiased-100k	2.1621	2.1385	-0.0236
26	100	Unbiased-100k	2.0997	2.082	-0.0177
27	100	Unbiased-100k	2.0874	2.0693	-0.0181
28	100	Unbiased-100k	2.1566	2.1282	-0.0284
29	110	Biased-100k	2.1491	1.9738	-0.1753
30	110	Biased-100k	2.2024	2.0575	-0.1449
31	110	Biased-100k	2.0597	1.9339	-0.1258
32	110	Biased-100k	2.1617	2.078	-0.0837
34	110	Biased-100k	2.2135	2.1223	-0.0912

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0522	2.1197	2.1625	0.059132	2.0488	2.1191	2.1619	0.061338	-0.0034	-0.0006	0.0022	0.0028
50	2.1194	2.1699	2.2685	0.058754	2.1026	2.1538	2.2612	0.063914	-0.0232	-0.01612	-0.0073	0.0065259
60	1.9909	2.1281	2.2372	0.089845	1.9152	2.0459	2.15	0.08484	-0.0928	-0.08224	-0.0714	0.0086581
100	2.0242	2.106	2.1621	0.056534	2.0014	2.0839	2.1385	0.054696	-0.0284	-0.02212	-0.0177	0.0044099
110	2.0597	2.1573	2.2135	0.060838	1.9339	2.0331	2.1223	0.077339	-0.1753	-0.12418	-0.0837	0.037985

Device Test: 29.9 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW4/7/7///90.9/634//1.8///@LOW_SIDE_OC_SINK)





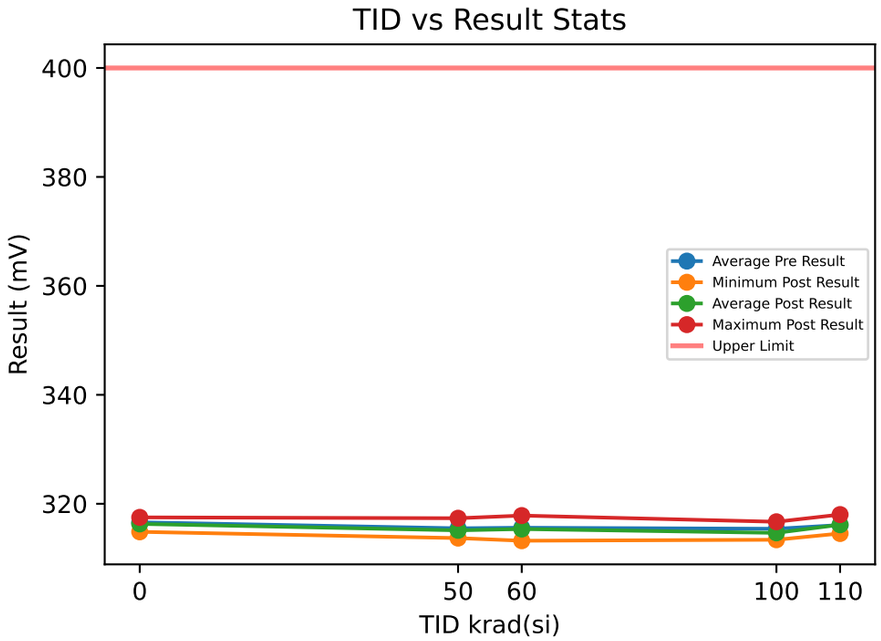
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

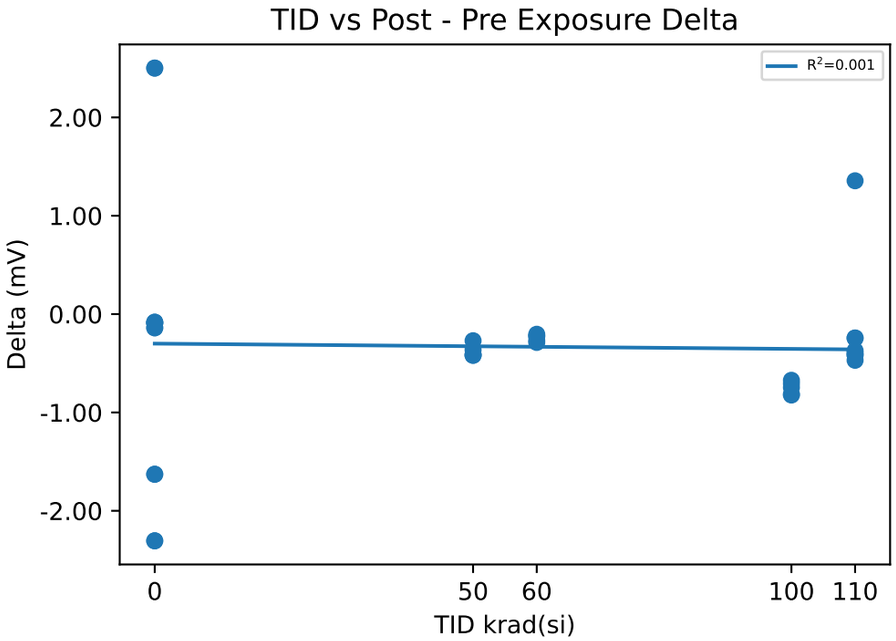
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.1605	2.1433	-0.0172
2	0	CU2	2.1692	2.1615	-0.0077
3	0	CU3	2.2076	2.1935	-0.0141
11	50	Unbiased-50k	2.1127	2.0895	-0.0232
12	50	Unbiased-50k	2.1368	2.099	-0.0378
13	50	Unbiased-50k	2.2048	2.1722	-0.0326
14	50	Unbiased-50k	2.2028	2.1655	-0.0373
16	50	Unbiased-50k	2.253	2.2121	-0.0409
17	60	Biased-50k	2.2285	2.1378	-0.0907
18	60	Biased-50k	2.3285	2.22	-0.1085
19	60	Biased-50k	2.3274	2.2113	-0.1161
20	60	Biased-50k	2.0763	1.9701	-0.1062
21	60	Biased-50k	2.0447	1.9599	-0.0848
24	100	Unbiased-100k	2.2661	2.2162	-0.0499
25	100	Unbiased-100k	2.189	2.1629	-0.0261
26	100	Unbiased-100k	2.119	2.078	-0.041
27	100	Unbiased-100k	2.0819	2.0235	-0.0584
28	100	Unbiased-100k	2.04	2.0002	-0.0398
29	110	Biased-100k	2.1487	1.9833	-0.1654
30	110	Biased-100k	2.4566	2.2814	-0.1752
31	110	Biased-100k	2.1929	2.0453	-0.1476
32	110	Biased-100k	2.3337	2.0101	-0.3236
34	110	Biased-100k	2.1791	2.0156	-0.1635

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1605	2.1791	2.2076	0.025062	2.1433	2.1661	2.1935	0.025414	-0.0172	-0.013	-0.0077	0.0048446
50	2.1127	2.182	2.253	0.056655	2.0895	2.1477	2.2121	0.052018	-0.0409	-0.03436	-0.0232	0.0069082
60	2.0447	2.2011	2.3285	0.13506	1.9599	2.0998	2.22	0.1272	-0.1161	-0.10126	-0.0848	0.013034
100	2.04	2.1392	2.2661	0.089604	2.0002	2.0962	2.2162	0.091762	-0.0584	-0.04304	-0.0261	0.012089
110	2.1487	2.2622	2.4566	0.1299	1.9833	2.0671	2.2814	0.12178	-0.3236	-0.19506	-0.1476	0.072535

Device Test: 30.1 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD1/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





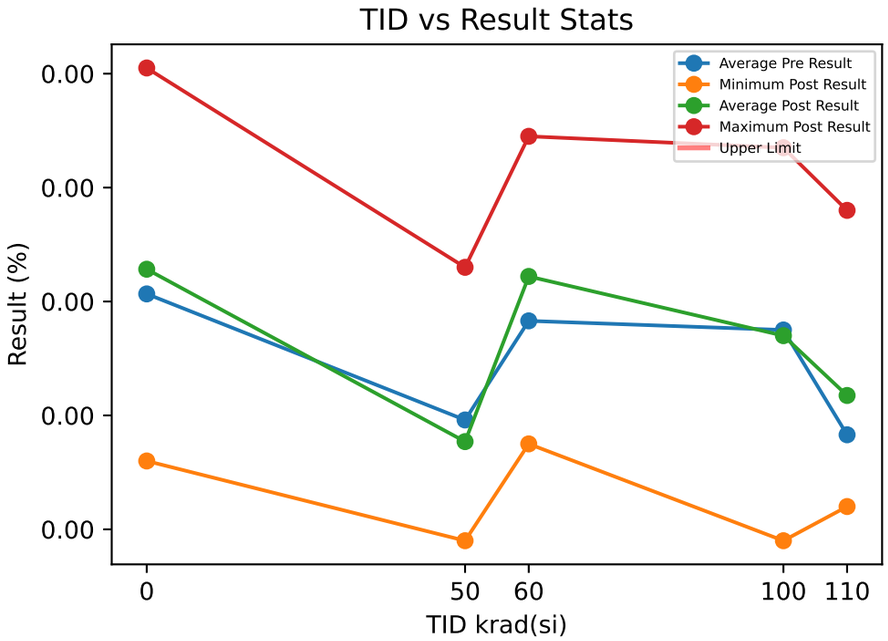
Test Results (Upper Limit = 400.0 (mV))

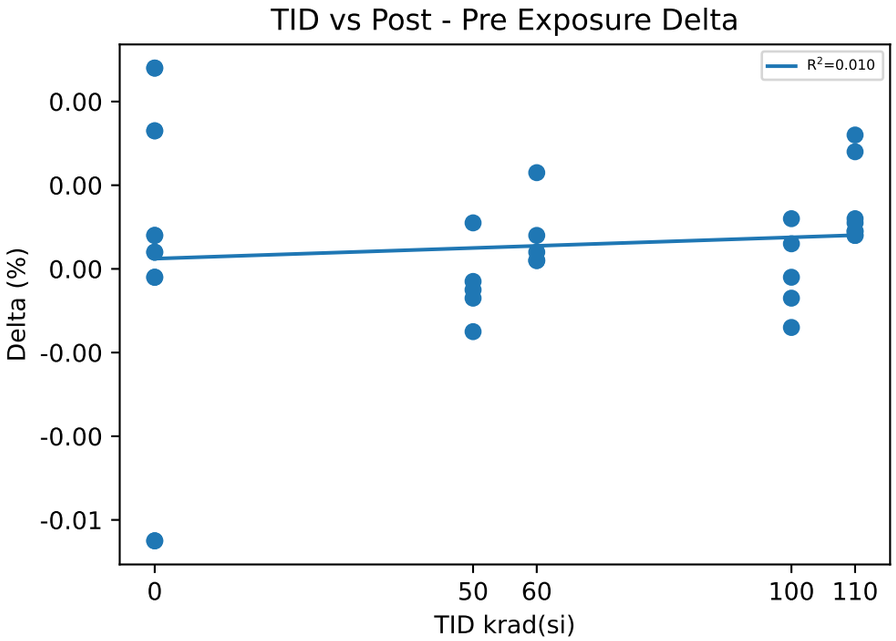
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	317.63	317.49	-0.1393
2	0	CU2	315	314.91	-0.0916
3	0	CU3	317.15	317.07	-0.0824
11	50	Unbiased-50k	315.28	314.92	-0.3638
12	50	Unbiased-50k	314.11	313.7	-0.4121
13	50	Unbiased-50k	314.7	314.28	-0.4192
14	50	Unbiased-50k	315.8	315.38	-0.4177
16	50	Unbiased-50k	317.62	317.35	-0.2705
17	60	Biased-50k	316.93	316.65	-0.2882
18	60	Biased-50k	313.42	313.22	-0.2048
19	60	Biased-50k	315.31	315.08	-0.2264
20	60	Biased-50k	314.3	314.03	-0.2686
21	60	Biased-50k	318.05	317.83	-0.2212
24	100	Unbiased-100k	316	315.18	-0.823
25	100	Unbiased-100k	314.07	313.39	-0.6728
26	100	Unbiased-100k	314.92	314.18	-0.7461
27	100	Unbiased-100k	314.65	313.84	-0.8143
28	100	Unbiased-100k	317.4	316.69	-0.7067
29	110	Biased-100k	315.91	315.44	-0.4699
30	110	Biased-100k	318.39	318.02	-0.3712
31	110	Biased-100k	316.34	315.95	-0.3926
32	110	Biased-100k	313.19	314.54	1.3556
34	110	Biased-100k	316.64	316.22	-0.415

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	315	316.59	317.63	1.3991	314.91	316.49	317.49	1.3836	-0.1393	-0.10443	-0.0824	0.030544
50	314.11	315.5	317.62	1.3405	313.7	315.12	317.35	1.3955	-0.4192	-0.37666	-0.2705	0.063611
60	313.42	315.6	318.05	1.8931	313.22	315.36	317.83	1.8853	-0.2882	-0.24184	-0.2048	0.035006
100	314.07	315.41	317.4	1.3162	313.39	314.66	316.69	1.3152	-0.823	-0.75258	-0.6728	0.065727
110	313.19	316.09	318.39	1.8772	314.54	316.04	318.02	1.2786	-0.4699	-0.05862	1.3556	0.79143

Test: 30.10 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_RISING





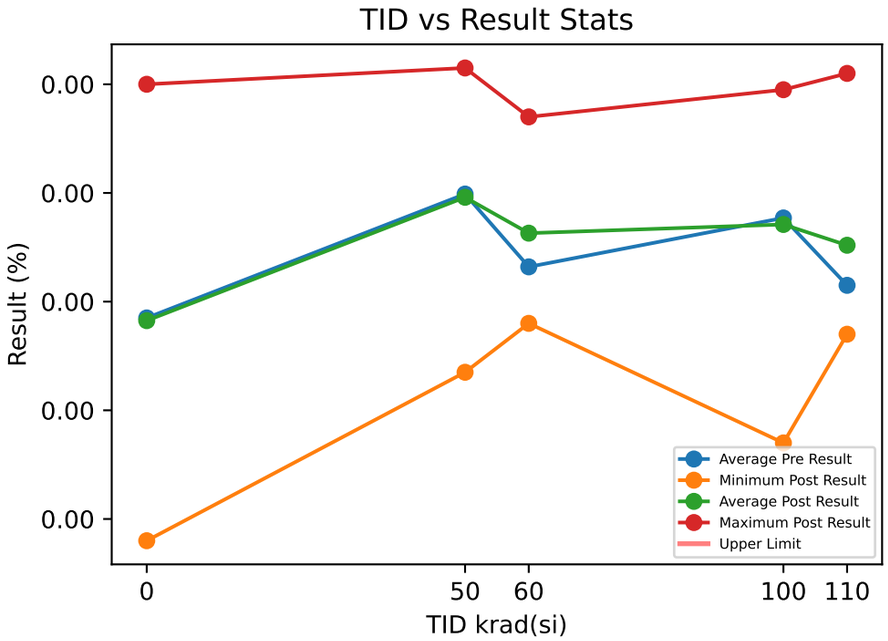
Test Results (No Limits Specified (%))

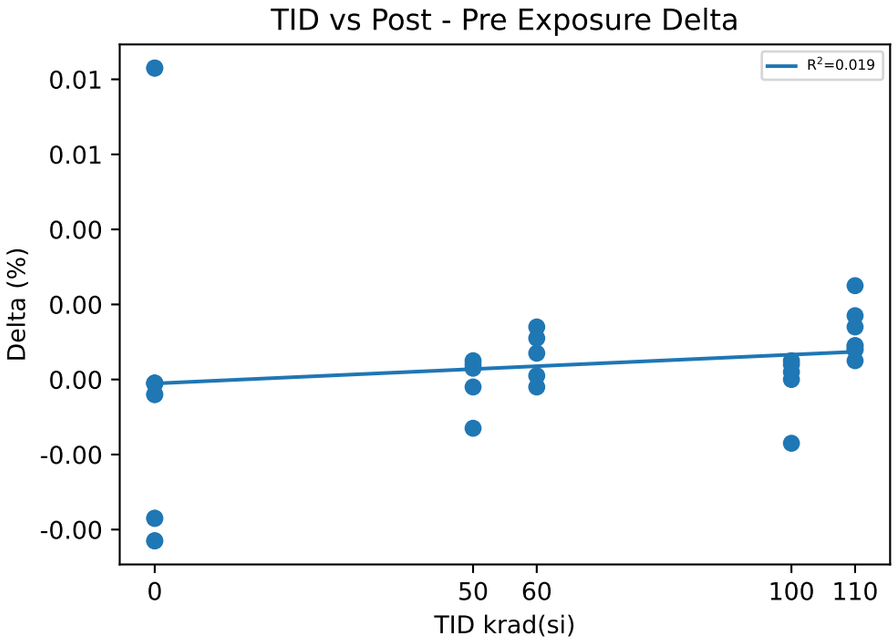
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.443e-13	9.441e-13	-0.0002
2	0	CU2	9.393e-13	9.401e-13	0.0008
3	0	CU3	9.368e-13	9.372e-13	0.0004
11	50	Unbiased-50k	9.395e-13	9.406e-13	0.0011
12	50	Unbiased-50k	9.367e-13	9.362e-13	-0.0005
13	50	Unbiased-50k	9.396e-13	9.381e-13	-0.0015
14	50	Unbiased-50k	9.377e-13	9.37e-13	-0.0007
16	50	Unbiased-50k	9.361e-13	9.358e-13	-0.0003
17	60	Biased-50k	9.373e-13	9.381e-13	0.0008
18	60	Biased-50k	9.413e-13	9.415e-13	0.0002
19	60	Biased-50k	9.371e-13	9.375e-13	0.0004
20	60	Biased-50k	9.427e-13	9.429e-13	0.0002
21	60	Biased-50k	9.399e-13	9.422e-13	0.0023
24	100	Unbiased-100k	9.388e-13	9.386e-13	-0.0002
25	100	Unbiased-100k	9.415e-13	9.427e-13	0.0012
26	100	Unbiased-100k	9.421e-13	9.407e-13	-0.0014
27	100	Unbiased-100k	9.386e-13	9.392e-13	0.0006
28	100	Unbiased-100k	9.365e-13	9.358e-13	-0.0007
29	110	Biased-100k	9.384e-13	9.416e-13	0.0032
30	110	Biased-100k	9.363e-13	9.375e-13	0.0012
31	110	Biased-100k	9.399e-13	9.41e-13	0.0011
32	110	Biased-100k	9.381e-13	9.409e-13	0.0028
34	110	Biased-100k	9.356e-13	9.364e-13	0.0008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.368e-13	9.4013e-13	9.443e-13	3.8188e-15	9.372e-13	9.4047e-13	9.441e-13	3.4646e-15	-0.0002	0.00033333	0.0008	0.00050332
50	9.361e-13	9.3792e-13	9.396e-13	1.5944e-15	9.358e-13	9.3754e-13	9.406e-13	1.923e-15	-0.0015	-0.00038	0.0011	0.00094446
60	9.371e-13	9.3966e-13	9.427e-13	2.4552e-15	9.375e-13	9.4044e-13	9.429e-13	2.4694e-15	0.0002	0.00078	0.0023	0.00088431
100	9.365e-13	9.395e-13	9.421e-13	2.2946e-15	9.358e-13	9.394e-13	9.427e-13	2.5603e-15	-0.0014	-0.0001	0.0012	0.0010296
110	9.356e-13	9.3766e-13	9.399e-13	1.7213e-15	9.364e-13	9.3948e-13	9.416e-13	2.3573e-15	0.0008	0.00182	0.0032	0.0010964

Test: 30.11 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_RISING





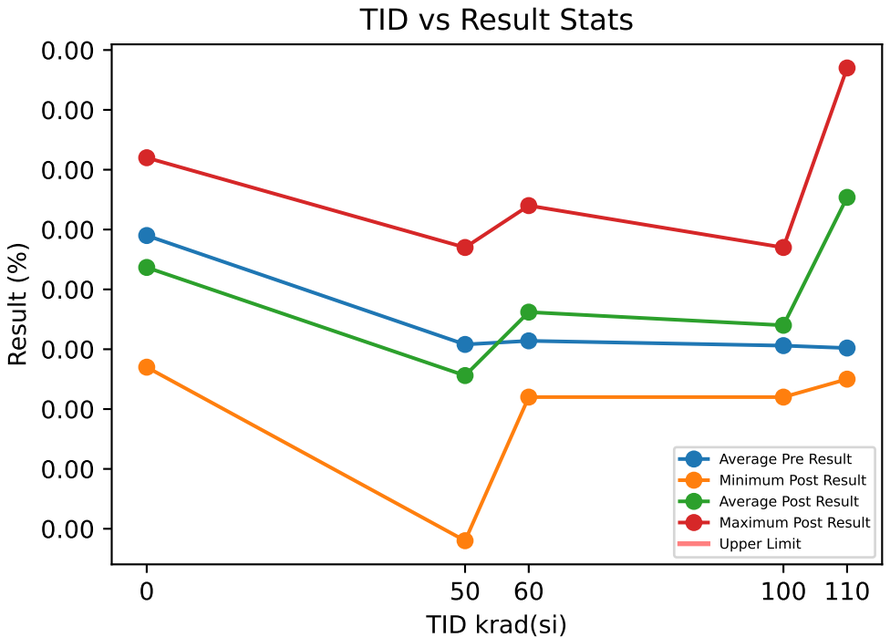
Test Results (No Limits Specified (%))

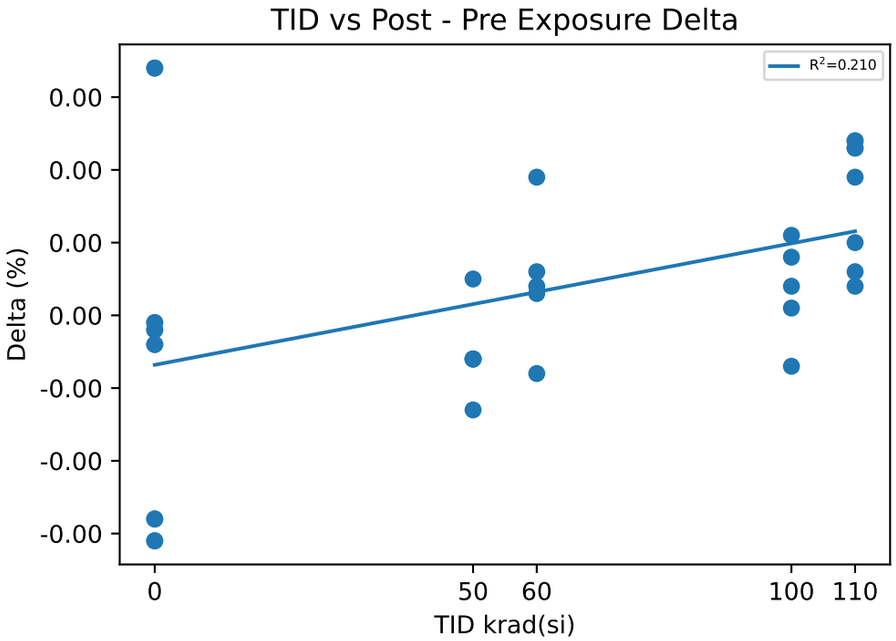
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.421e-13	9.42e-13	-0.0001
2	0	CU2	9.337e-13	9.336e-13	-0.0001
3	0	CU3	9.373e-13	9.369e-13	-0.0004
11	50	Unbiased-50k	9.363e-13	9.367e-13	0.0004
12	50	Unbiased-50k	9.415e-13	9.42e-13	0.0005
13	50	Unbiased-50k	9.389e-13	9.376e-13	-0.0013
14	50	Unbiased-50k	9.407e-13	9.41e-13	0.0003
16	50	Unbiased-50k	9.425e-13	9.423e-13	-0.0002
17	60	Biased-50k	9.394e-13	9.401e-13	0.0007
18	60	Biased-50k	9.375e-13	9.386e-13	0.0011
19	60	Biased-50k	9.4e-13	9.414e-13	0.0014
20	60	Biased-50k	9.375e-13	9.376e-13	0.0001
21	60	Biased-50k	9.388e-13	9.386e-13	-0.0002
24	100	Unbiased-100k	9.354e-13	9.354e-13	0
25	100	Unbiased-100k	9.415e-13	9.419e-13	0.0004
26	100	Unbiased-100k	9.394e-13	9.396e-13	0.0002
27	100	Unbiased-100k	9.393e-13	9.398e-13	0.0005
28	100	Unbiased-100k	9.421e-13	9.404e-13	-0.0017
29	110	Biased-100k	9.379e-13	9.404e-13	0.0025
30	110	Biased-100k	9.417e-13	9.422e-13	0.0005
31	110	Biased-100k	9.357e-13	9.374e-13	0.0017
32	110	Biased-100k	9.391e-13	9.405e-13	0.0014
34	110	Biased-100k	9.371e-13	9.379e-13	0.0008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.337e-13	9.377e-13	9.421e-13	4.2143e-15	9.336e-13	9.375e-13	9.42e-13	4.232e-15	-0.0004	-0.0002	-0.0001	0.00017321
50	9.363e-13	9.3998e-13	9.425e-13	2.4438e-15	9.367e-13	9.3992e-13	9.423e-13	2.5936e-15	-0.0013	-6e-05	0.0005	0.00074364
60	9.375e-13	9.3864e-13	9.4e-13	1.1238e-15	9.376e-13	9.3926e-13	9.414e-13	1.4926e-15	-0.0002	0.00062	0.0014	0.00066858
100	9.354e-13	9.3954e-13	9.421e-13	2.6274e-15	9.354e-13	9.3942e-13	9.419e-13	2.4212e-15	-0.0017	-0.00012	0.0005	0.00090388
110	9.357e-13	9.383e-13	9.417e-13	2.2672e-15	9.374e-13	9.3968e-13	9.422e-13	1.9942e-15	0.0005	0.00138	0.0025	0.00078549

Test: 30.12 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_RISING





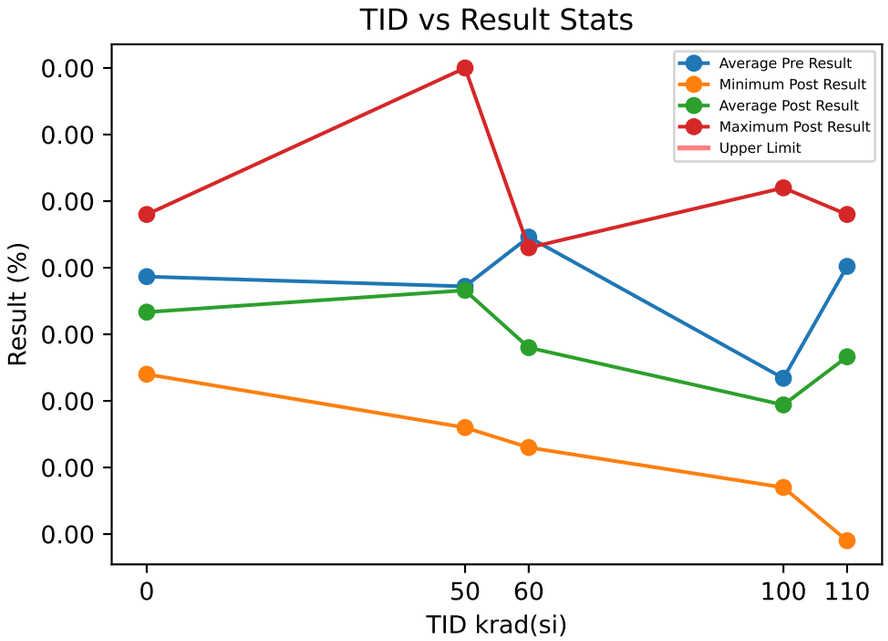
Test Results (No Limits Specified (%))

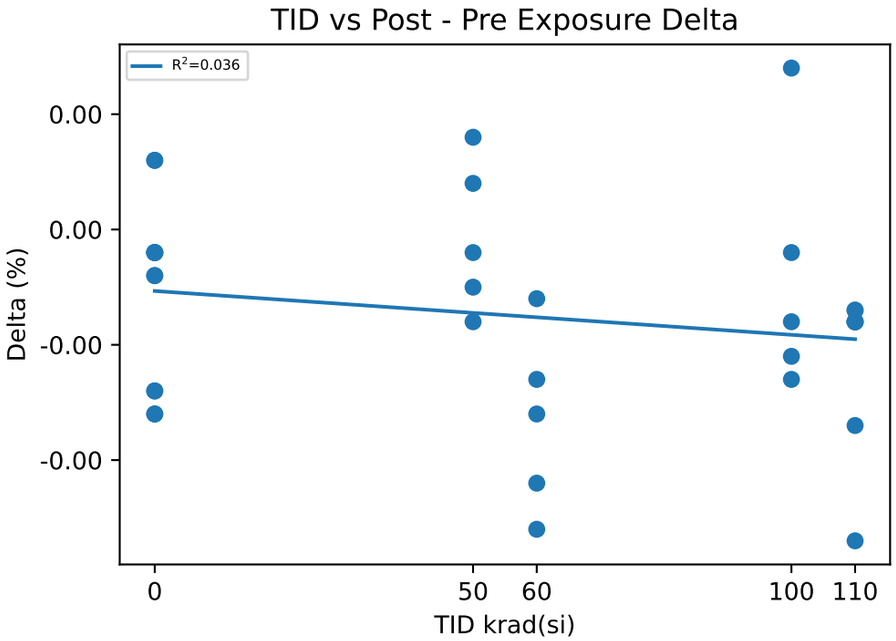
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.424e-13	9.422e-13	-0.0002
2	0	CU2	9.388e-13	9.387e-13	-0.0001
3	0	CU3	9.415e-13	9.411e-13	-0.0004
11	50	Unbiased-50k	9.374e-13	9.368e-13	-0.0006
12	50	Unbiased-50k	9.407e-13	9.394e-13	-0.0013
13	50	Unbiased-50k	9.407e-13	9.401e-13	-0.0006
14	50	Unbiased-50k	9.364e-13	9.358e-13	-0.0006
16	50	Unbiased-50k	9.402e-13	9.407e-13	0.0005
17	60	Biased-50k	9.402e-13	9.394e-13	-0.0008
18	60	Biased-50k	9.403e-13	9.406e-13	0.0003
19	60	Biased-50k	9.381e-13	9.385e-13	0.0004
20	60	Biased-50k	9.395e-13	9.414e-13	0.0019
21	60	Biased-50k	9.376e-13	9.382e-13	0.0006
24	100	Unbiased-100k	9.374e-13	9.382e-13	0.0008
25	100	Unbiased-100k	9.378e-13	9.389e-13	0.0011
26	100	Unbiased-100k	9.396e-13	9.389e-13	-0.0007
27	100	Unbiased-100k	9.403e-13	9.407e-13	0.0004
28	100	Unbiased-100k	9.402e-13	9.403e-13	0.0001
29	110	Biased-100k	9.385e-13	9.391e-13	0.0006
30	110	Biased-100k	9.381e-13	9.385e-13	0.0004
31	110	Biased-100k	9.381e-13	9.391e-13	0.001
32	110	Biased-100k	9.391e-13	9.41e-13	0.0019
34	110	Biased-100k	9.413e-13	9.436e-13	0.0023

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.388e-13	9.409e-13	9.424e-13	1.8735e-15	9.387e-13	9.4067e-13	9.422e-13	1.7898e-15	-0.0004	-0.00023333	-0.0001	0.00015275
50	9.364e-13	9.3908e-13	9.407e-13	2.0315e-15	9.358e-13	9.3856e-13	9.407e-13	2.1431e-15	-0.0013	-0.00052	0.0005	0.00064576
60	9.376e-13	9.3914e-13	9.403e-13	1.23e-15	9.382e-13	9.3962e-13	9.414e-13	1.3646e-15	-0.0008	0.00048	0.0019	0.00096281
100	9.374e-13	9.3906e-13	9.403e-13	1.3667e-15	9.382e-13	9.394e-13	9.407e-13	1.0536e-15	-0.0007	0.00034	0.0011	0.00069498
110	9.381e-13	9.3902e-13	9.413e-13	1.3387e-15	9.385e-13	9.4026e-13	9.436e-13	2.0912e-15	0.0004	0.00124	0.0023	0.00082644

Test: 30.13 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_RISING





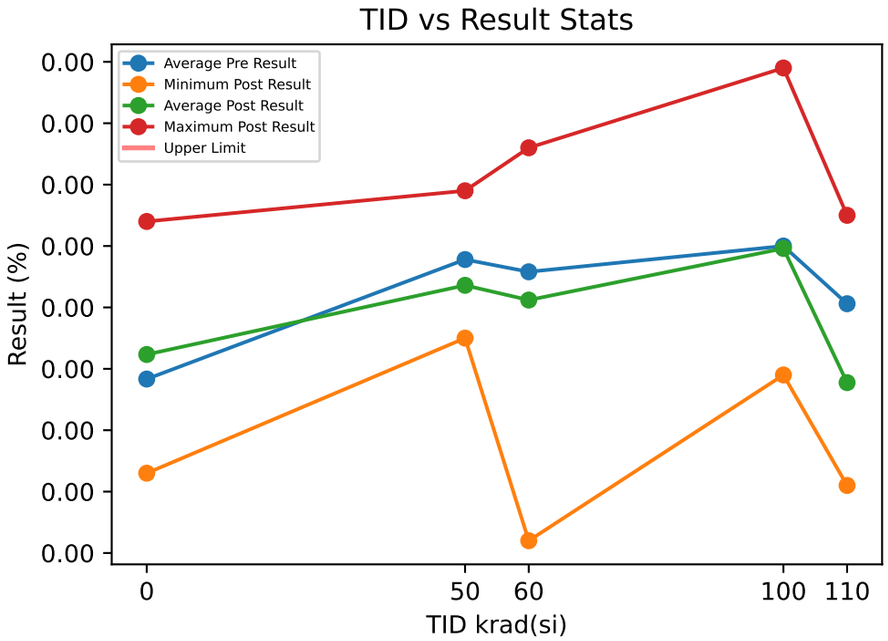
Test Results (No Limits Specified (%))

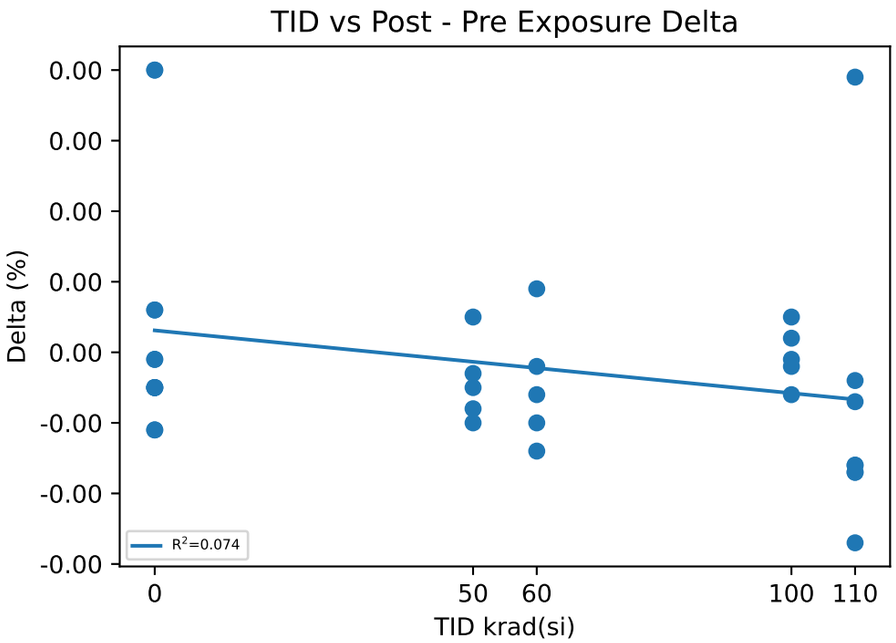
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0906e-12	1.0904e-12	-0.0002
2	0	CU2	1.0918e-12	1.0916e-12	-0.0002
3	0	CU3	1.0932e-12	1.0928e-12	-0.0004
11	50	Unbiased-50k	1.0904e-12	1.0902e-12	-0.0002
12	50	Unbiased-50k	1.09e-12	1.0908e-12	0.0008
13	50	Unbiased-50k	1.0932e-12	1.0927e-12	-0.0005
14	50	Unbiased-50k	1.0946e-12	1.095e-12	0.0004
16	50	Unbiased-50k	1.0904e-12	1.0896e-12	-0.0008
17	60	Biased-50k	1.0936e-12	1.0923e-12	-0.0013
18	60	Biased-50k	1.0924e-12	1.0918e-12	-0.0006
19	60	Biased-50k	1.0915e-12	1.0893e-12	-0.0022
20	60	Biased-50k	1.0921e-12	1.0905e-12	-0.0016
21	60	Biased-50k	1.0927e-12	1.0901e-12	-0.0026
24	100	Unbiased-100k	1.0902e-12	1.0889e-12	-0.0013
25	100	Unbiased-100k	1.0898e-12	1.0887e-12	-0.0011
26	100	Unbiased-100k	1.0887e-12	1.0901e-12	0.0014
27	100	Unbiased-100k	1.089e-12	1.0888e-12	-0.0002
28	100	Unbiased-100k	1.094e-12	1.0932e-12	-0.0008
29	110	Biased-100k	1.094e-12	1.0923e-12	-0.0017
30	110	Biased-100k	1.0886e-12	1.0879e-12	-0.0007
31	110	Biased-100k	1.0935e-12	1.0928e-12	-0.0007
32	110	Biased-100k	1.0926e-12	1.0899e-12	-0.0027
34	110	Biased-100k	1.0914e-12	1.0906e-12	-0.0008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0906e-12	1.0919e-12	1.0932e-12	1.3013e-15	1.0904e-12	1.0916e-12	1.0928e-12	1.2e-15	-0.0004	-0.00026667	-0.0002	0.00011547
50	1.09e-12	1.0917e-12	1.0946e-12	2.0572e-15	1.0896e-12	1.0917e-12	1.095e-12	2.1995e-15	-0.0008	-6e-05	0.0008	0.00065422
60	1.0915e-12	1.0925e-12	1.0936e-12	7.7653e-16	1.0893e-12	1.0908e-12	1.0923e-12	1.2329e-15	-0.0026	-0.00166	-0.0006	0.00077974
100	1.0887e-12	1.0903e-12	1.094e-12	2.1326e-15	1.0887e-12	1.0899e-12	1.0932e-12	1.9087e-15	-0.0013	-0.0004	0.0014	0.0010886
110	1.0886e-12	1.092e-12	1.094e-12	2.1522e-15	1.0879e-12	1.0907e-12	1.0928e-12	1.966e-15	-0.0027	-0.00132	-0.0007	0.00087864

Test: 30.14 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_RISING





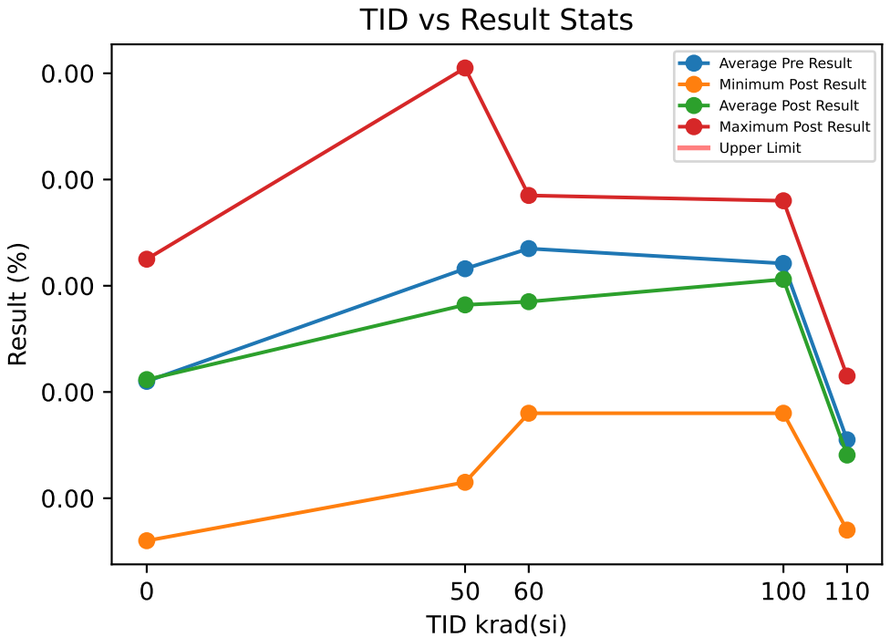
Test Results (No Limits Specified (%))

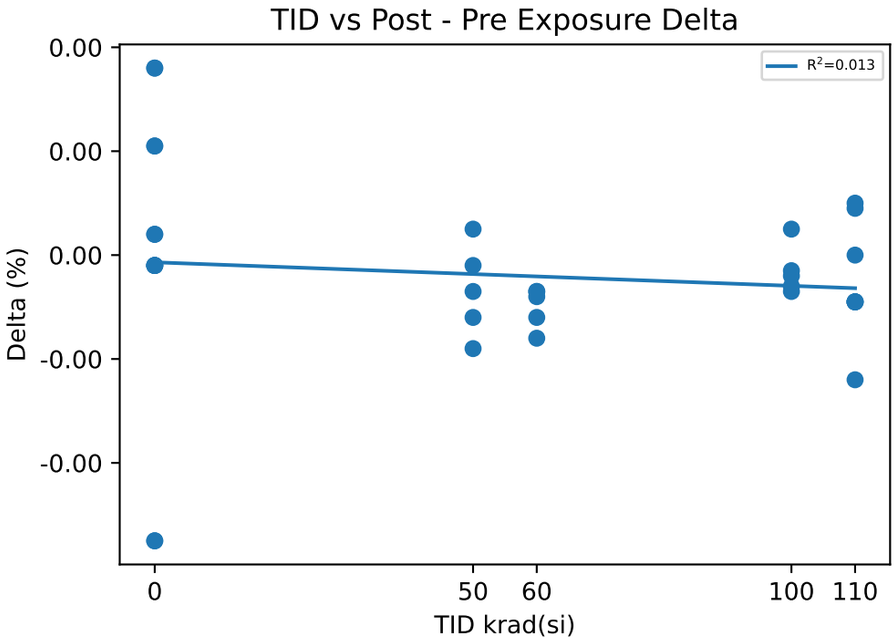
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0917e-12	1.0923e-12	0.0006
2	0	CU2	1.0884e-12	1.0883e-12	-0.0001
3	0	CU3	1.0894e-12	1.0889e-12	-0.0005
11	50	Unbiased-50k	1.0915e-12	1.0912e-12	-0.0003
12	50	Unbiased-50k	1.0939e-12	1.0929e-12	-0.001
13	50	Unbiased-50k	1.0916e-12	1.0911e-12	-0.0005
14	50	Unbiased-50k	1.0906e-12	1.0911e-12	0.0005
16	50	Unbiased-50k	1.0913e-12	1.0905e-12	-0.0008
17	60	Biased-50k	1.0882e-12	1.0872e-12	-0.001
18	60	Biased-50k	1.0934e-12	1.092e-12	-0.0014
19	60	Biased-50k	1.0924e-12	1.0918e-12	-0.0006
20	60	Biased-50k	1.0938e-12	1.0936e-12	-0.0002
21	60	Biased-50k	1.0901e-12	1.091e-12	0.0009
24	100	Unbiased-100k	1.091e-12	1.0912e-12	0.0002
25	100	Unbiased-100k	1.0901e-12	1.0899e-12	-0.0002
26	100	Unbiased-100k	1.0934e-12	1.0939e-12	0.0005
27	100	Unbiased-100k	1.095e-12	1.0949e-12	-0.0001
28	100	Unbiased-100k	1.0905e-12	1.0899e-12	-0.0006
29	110	Biased-100k	1.095e-12	1.0923e-12	-0.0027
30	110	Biased-100k	1.0892e-12	1.0885e-12	-0.0007
31	110	Biased-100k	1.0927e-12	1.0923e-12	-0.0004
32	110	Biased-100k	1.0886e-12	1.0925e-12	0.0039
34	110	Biased-100k	1.0898e-12	1.0881e-12	-0.0017

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0884e-12	1.0898e-12	1.0917e-12	1.6921e-15	1.0883e-12	1.0898e-12	1.0923e-12	2.1572e-15	-0.0005	7.4015e-17	0.0006	0.00055678
50	1.0906e-12	1.0918e-12	1.0939e-12	1.2478e-15	1.0905e-12	1.0914e-12	1.0929e-12	9.0443e-16	-0.001	-0.00042	0.0005	0.00058052
60	1.0882e-12	1.0916e-12	1.0938e-12	2.3732e-15	1.0872e-12	1.0911e-12	1.0936e-12	2.3858e-15	-0.0014	-0.00046	0.0009	0.00088204
100	1.0901e-12	1.092e-12	1.095e-12	2.1107e-15	1.0899e-12	1.092e-12	1.0949e-12	2.3169e-15	-0.0006	-4e-05	0.0005	0.00041593
110	1.0886e-12	1.0911e-12	1.095e-12	2.707e-15	1.0881e-12	1.0907e-12	1.0925e-12	2.2334e-15	-0.0027	-0.00032	0.0039	0.0025263

Test: 30.15 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_RISING





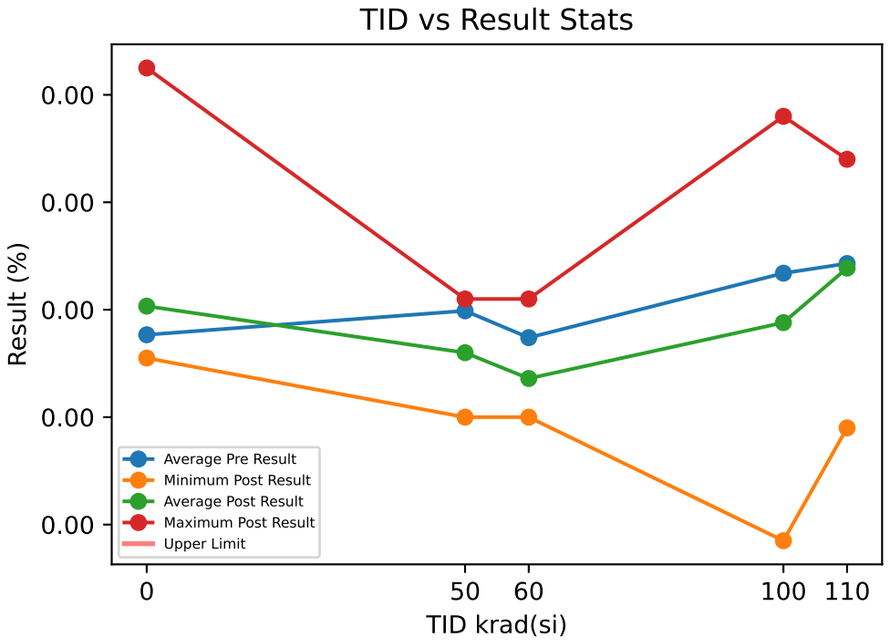
Test Results (No Limits Specified (%))

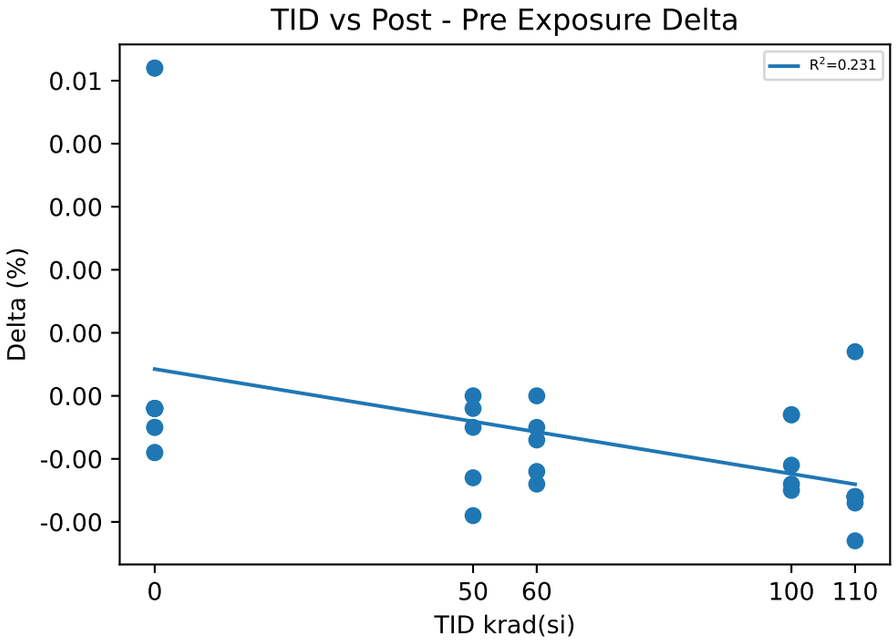
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0927e-12	1.0925e-12	-0.0002
2	0	CU2	1.0904e-12	1.0902e-12	-0.0002
3	0	CU3	1.0875e-12	1.0879e-12	0.0004
11	50	Unbiased-50k	1.0923e-12	1.0905e-12	-0.0018
12	50	Unbiased-50k	1.0963e-12	1.0961e-12	-0.0002
13	50	Unbiased-50k	1.0906e-12	1.0911e-12	0.0005
14	50	Unbiased-50k	1.0895e-12	1.0883e-12	-0.0012
16	50	Unbiased-50k	1.0929e-12	1.0922e-12	-0.0007
17	60	Biased-50k	1.0924e-12	1.0912e-12	-0.0012
18	60	Biased-50k	1.0939e-12	1.0923e-12	-0.0016
19	60	Biased-50k	1.0945e-12	1.0937e-12	-0.0008
20	60	Biased-50k	1.0903e-12	1.0896e-12	-0.0007
21	60	Biased-50k	1.0924e-12	1.0917e-12	-0.0007
24	100	Unbiased-100k	1.0902e-12	1.0896e-12	-0.0006
25	100	Unbiased-100k	1.0939e-12	1.0936e-12	-0.0003
26	100	Unbiased-100k	1.0939e-12	1.0935e-12	-0.0004
27	100	Unbiased-100k	1.0921e-12	1.0926e-12	0.0005
28	100	Unbiased-100k	1.092e-12	1.0913e-12	-0.0007
29	110	Biased-100k	1.0903e-12	1.0903e-12	0
30	110	Biased-100k	1.0871e-12	1.0881e-12	0.001
31	110	Biased-100k	1.0898e-12	1.0874e-12	-0.0024
32	110	Biased-100k	1.0886e-12	1.0895e-12	0.0009
34	110	Biased-100k	1.0897e-12	1.0888e-12	-0.0009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0875e-12	1.0902e-12	1.0927e-12	2.6058e-15	1.0879e-12	1.0902e-12	1.0925e-12	2.3e-15	-0.0002	7.4015e-17	0.0004	0.00034641
50	1.0895e-12	1.0923e-12	1.0963e-12	2.6023e-15	1.0883e-12	1.0916e-12	1.0961e-12	2.8702e-15	-0.0018	-0.00068	0.0005	0.00088713
60	1.0903e-12	1.0927e-12	1.0945e-12	1.6294e-15	1.0896e-12	1.0917e-12	1.0937e-12	1.5017e-15	-0.0016	-0.001	-0.0007	0.0003937
100	1.0902e-12	1.0924e-12	1.0939e-12	1.5482e-15	1.0896e-12	1.0921e-12	1.0936e-12	1.6843e-15	-0.0007	-0.0003	0.0005	0.00047434
110	1.0871e-12	1.0891e-12	1.0903e-12	1.2787e-15	1.0874e-12	1.0888e-12	1.0903e-12	1.1389e-15	-0.0024	-0.00028	0.001	0.0014132

Test: 30.16 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_RISING





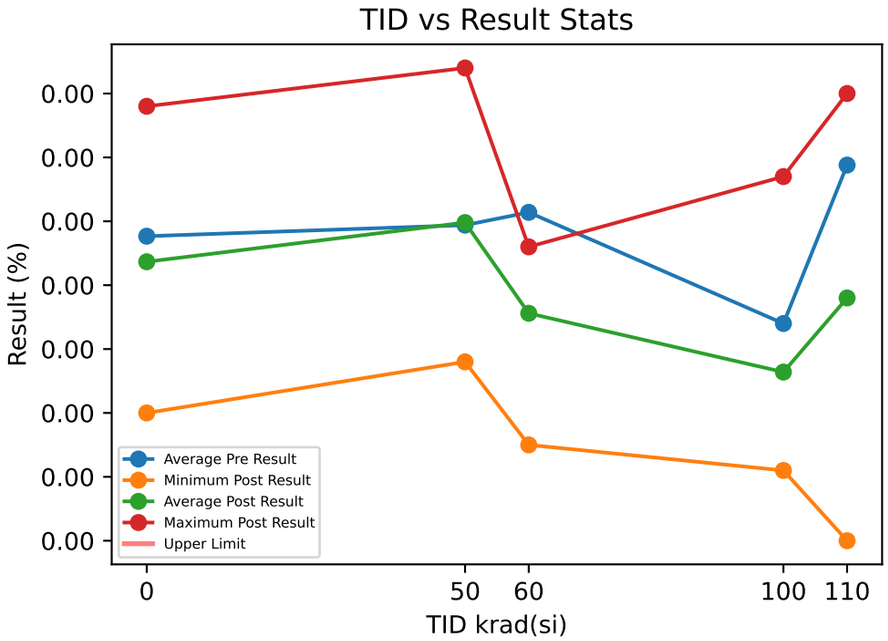
Test Results (No Limits Specified (%))

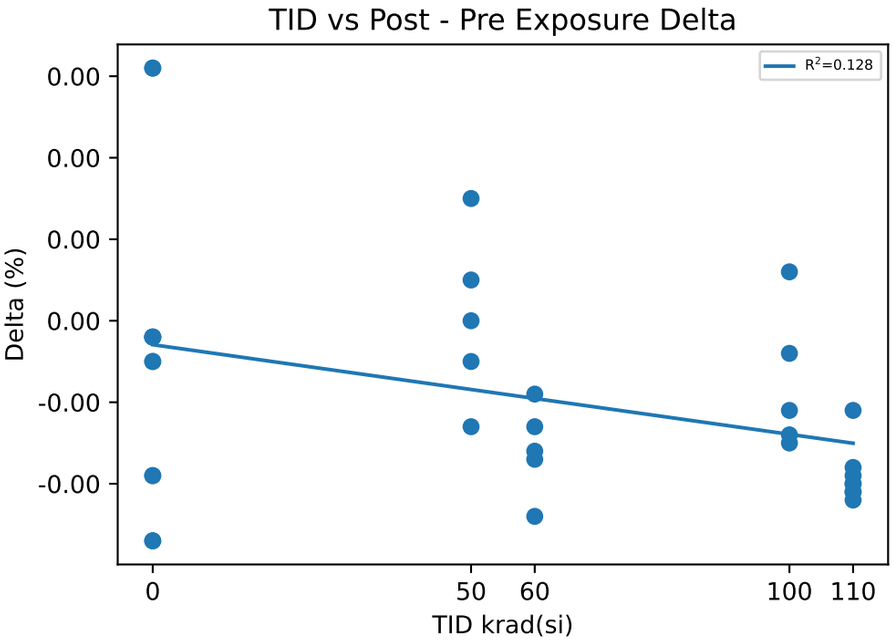
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0913e-12	1.0911e-12	-0.0002
2	0	CU2	1.0913e-12	1.0911e-12	-0.0002
3	0	CU3	1.092e-12	1.0915e-12	-0.0005
11	50	Unbiased-50k	1.0934e-12	1.0915e-12	-0.0019
12	50	Unbiased-50k	1.091e-12	1.091e-12	0
13	50	Unbiased-50k	1.0926e-12	1.0913e-12	-0.0013
14	50	Unbiased-50k	1.0905e-12	1.09e-12	-0.0005
16	50	Unbiased-50k	1.0924e-12	1.0922e-12	-0.0002
17	60	Biased-50k	1.0913e-12	1.0901e-12	-0.0012
18	60	Biased-50k	1.0915e-12	1.0901e-12	-0.0014
19	60	Biased-50k	1.0917e-12	1.0912e-12	-0.0005
20	60	Biased-50k	1.0907e-12	1.09e-12	-0.0007
21	60	Biased-50k	1.0922e-12	1.0922e-12	0
24	100	Unbiased-100k	1.0924e-12	1.0909e-12	-0.0015
25	100	Unbiased-100k	1.088e-12	1.0877e-12	-0.0003
26	100	Unbiased-100k	1.0959e-12	1.0956e-12	-0.0003
27	100	Unbiased-100k	1.0954e-12	1.0943e-12	-0.0011
28	100	Unbiased-100k	1.0917e-12	1.0903e-12	-0.0014
29	110	Biased-100k	1.0915e-12	1.0898e-12	-0.0017
30	110	Biased-100k	1.092e-12	1.0904e-12	-0.0016
31	110	Biased-100k	1.0926e-12	1.0903e-12	-0.0023
32	110	Biased-100k	1.0918e-12	1.0925e-12	0.0007
34	110	Biased-100k	1.0964e-12	1.0948e-12	-0.0016

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0913e-12	1.0915e-12	1.092e-12	4.0415e-16	1.0911e-12	1.0912e-12	1.0915e-12	2.3094e-16	-0.0005	-0.0003	-0.0002	0.00017321
50	1.0905e-12	1.092e-12	1.0934e-12	1.1967e-15	1.09e-12	1.0912e-12	1.0922e-12	8.0312e-16	-0.0019	-0.00078	0	0.00079812
60	1.0907e-12	1.0915e-12	1.0922e-12	5.4955e-16	1.09e-12	1.0907e-12	1.0922e-12	9.6281e-16	-0.0014	-0.00076	0	0.00055946
100	1.088e-12	1.0927e-12	1.0959e-12	3.1901e-15	1.0877e-12	1.0918e-12	1.0956e-12	3.184e-15	-0.0015	-0.00092	-0.0003	0.00058481
110	1.0915e-12	1.0929e-12	1.0964e-12	2.0194e-15	1.0898e-12	1.0916e-12	1.0948e-12	2.0864e-15	-0.0023	-0.0013	0.0007	0.0011554

st: 30.17 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_FALLIN





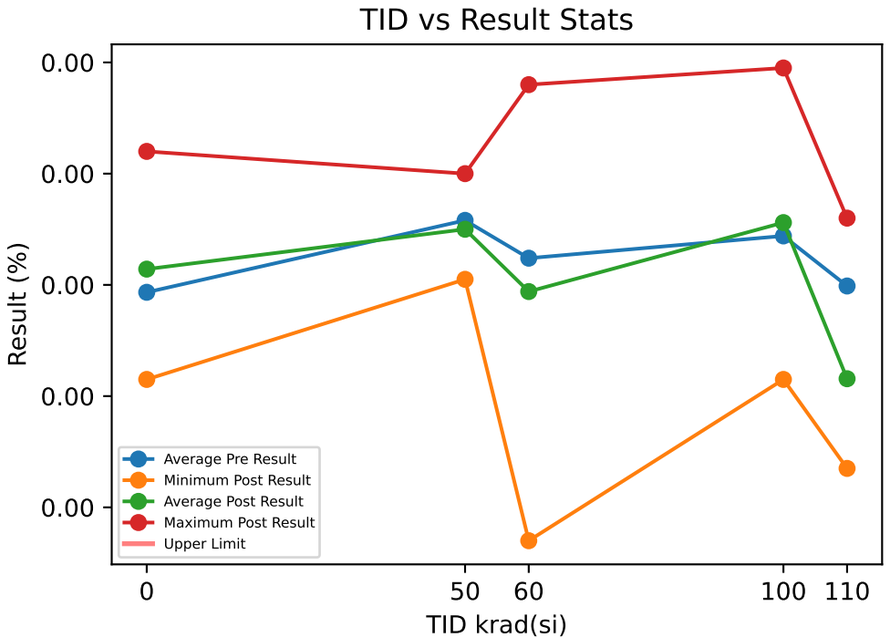
Test Results (No Limits Specified (%))

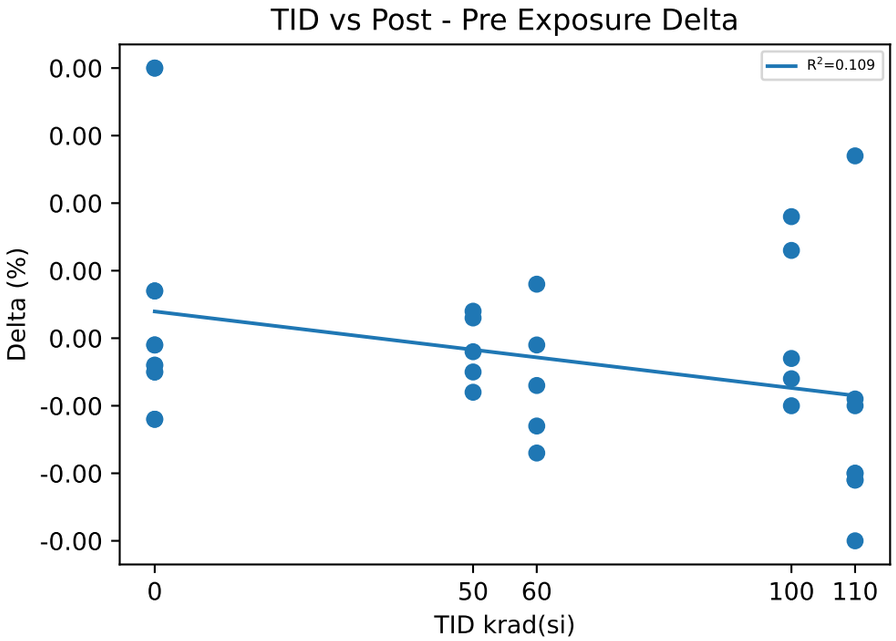
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0582e-12	1.058e-12	-0.0002
2	0	CU2	1.0608e-12	1.0606e-12	-0.0002
3	0	CU3	1.0633e-12	1.0628e-12	-0.0005
11	50	Unbiased-50k	1.0612e-12	1.0599e-12	-0.0013
12	50	Unbiased-50k	1.0594e-12	1.0609e-12	0.0015
13	50	Unbiased-50k	1.0624e-12	1.0619e-12	-0.0005
14	50	Unbiased-50k	1.0629e-12	1.0634e-12	0.0005
16	50	Unbiased-50k	1.0588e-12	1.0588e-12	0
17	60	Biased-50k	1.0619e-12	1.0606e-12	-0.0013
18	60	Biased-50k	1.0607e-12	1.0598e-12	-0.0009
19	60	Biased-50k	1.0599e-12	1.0575e-12	-0.0024
20	60	Biased-50k	1.0622e-12	1.0605e-12	-0.0017
21	60	Biased-50k	1.061e-12	1.0594e-12	-0.0016
24	100	Unbiased-100k	1.0594e-12	1.058e-12	-0.0014
25	100	Unbiased-100k	1.0582e-12	1.0571e-12	-0.0011
26	100	Unbiased-100k	1.058e-12	1.0586e-12	0.0006
27	100	Unbiased-100k	1.0582e-12	1.0578e-12	-0.0004
28	100	Unbiased-100k	1.0632e-12	1.0617e-12	-0.0015
29	110	Biased-100k	1.0649e-12	1.063e-12	-0.0019
30	110	Biased-100k	1.0578e-12	1.056e-12	-0.0018
31	110	Biased-100k	1.0635e-12	1.0624e-12	-0.0011
32	110	Biased-100k	1.0618e-12	1.0596e-12	-0.0022
34	110	Biased-100k	1.0614e-12	1.0593e-12	-0.0021

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0582e-12	1.0608e-12	1.0633e-12	2.5502e-15	1.058e-12	1.0605e-12	1.0628e-12	2.4028e-15	-0.0005	-0.0003	-0.0002	0.00017321
50	1.0588e-12	1.0609e-12	1.0629e-12	1.8022e-15	1.0588e-12	1.061e-12	1.0634e-12	1.7768e-15	-0.0013	4e-05	0.0015	0.0010526
60	1.0599e-12	1.0611e-12	1.0622e-12	9.2898e-16	1.0575e-12	1.0596e-12	1.0606e-12	1.2542e-15	-0.0024	-0.00158	-0.0009	0.00055408
100	1.058e-12	1.0594e-12	1.0632e-12	2.1954e-15	1.0571e-12	1.0586e-12	1.0617e-12	1.7925e-15	-0.0015	-0.00076	0.0006	0.0008735
110	1.0578e-12	1.0619e-12	1.0649e-12	2.6753e-15	1.056e-12	1.0601e-12	1.063e-12	2.8014e-15	-0.0022	-0.00182	-0.0011	0.00043243

st: 30.18 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_FALLIN





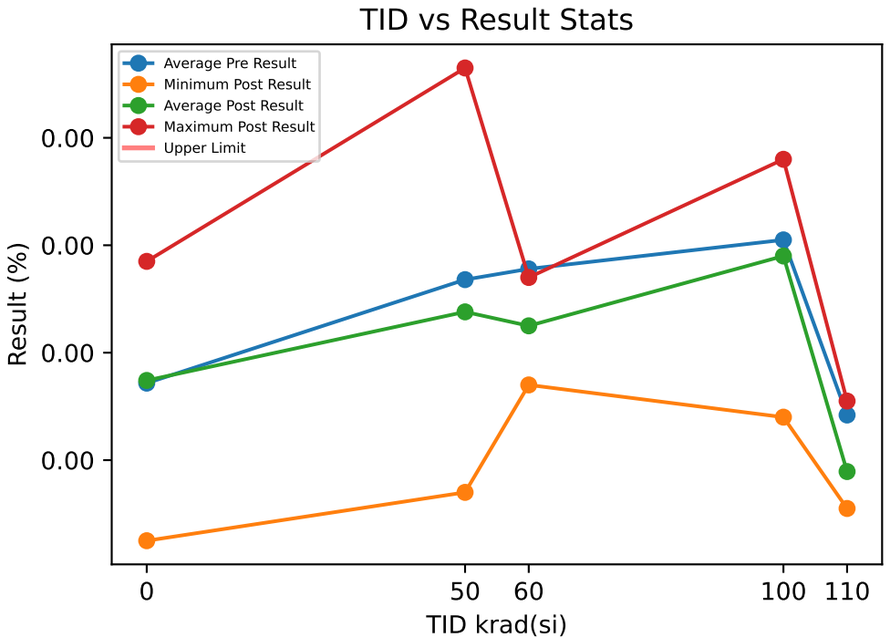
Test Results (No Limits Specified (%))

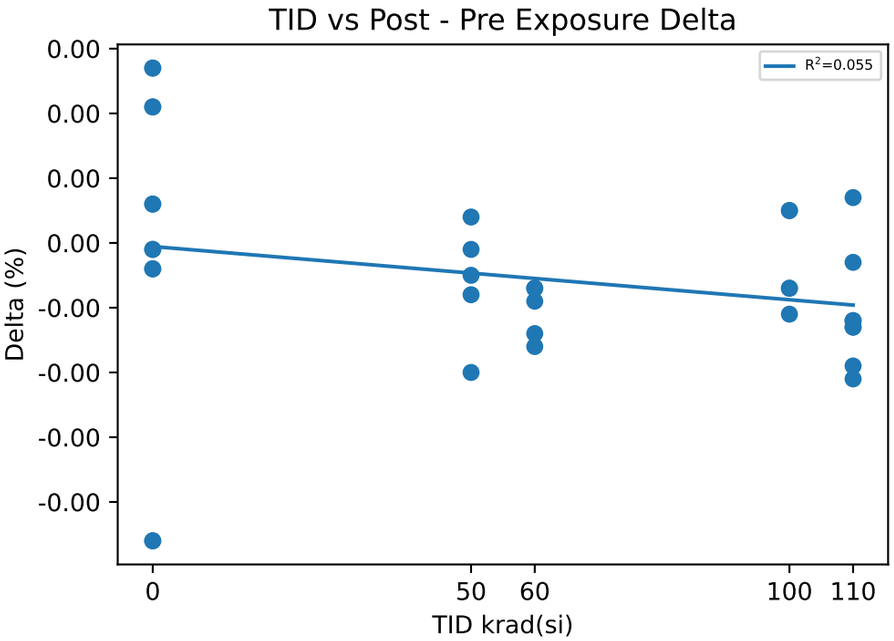
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0617e-12	1.0624e-12	0.0007
2	0	CU2	1.0584e-12	1.0583e-12	-0.0001
3	0	CU3	1.0595e-12	1.0591e-12	-0.0004
11	50	Unbiased-50k	1.0606e-12	1.0601e-12	-0.0005
12	50	Unbiased-50k	1.0614e-12	1.0612e-12	-0.0002
13	50	Unbiased-50k	1.0617e-12	1.062e-12	0.0003
14	50	Unbiased-50k	1.0607e-12	1.0611e-12	0.0004
16	50	Unbiased-50k	1.0614e-12	1.0606e-12	-0.0008
17	60	Biased-50k	1.0567e-12	1.0554e-12	-0.0013
18	60	Biased-50k	1.0618e-12	1.0601e-12	-0.0017
19	60	Biased-50k	1.0616e-12	1.0609e-12	-0.0007
20	60	Biased-50k	1.0637e-12	1.0636e-12	-0.0001
21	60	Biased-50k	1.0586e-12	1.0594e-12	0.0008
24	100	Unbiased-100k	1.0586e-12	1.0604e-12	0.0018
25	100	Unbiased-100k	1.0586e-12	1.0583e-12	-0.0003
26	100	Unbiased-100k	1.0626e-12	1.0639e-12	0.0013
27	100	Unbiased-100k	1.0649e-12	1.0639e-12	-0.001
28	100	Unbiased-100k	1.0597e-12	1.0591e-12	-0.0006
29	110	Biased-100k	1.0642e-12	1.0612e-12	-0.003
30	110	Biased-100k	1.0577e-12	1.0567e-12	-0.001
31	110	Biased-100k	1.0611e-12	1.0602e-12	-0.0009
32	110	Biased-100k	1.0579e-12	1.0606e-12	0.0027
34	110	Biased-100k	1.059e-12	1.0569e-12	-0.0021

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0584e-12	1.0599e-12	1.0617e-12	1.6803e-15	1.0583e-12	1.0599e-12	1.0624e-12	2.1733e-15	-0.0004	6.6667e-05	0.0007	0.00056862
50	1.0606e-12	1.0612e-12	1.0617e-12	4.827e-16	1.0601e-12	1.061e-12	1.062e-12	7.1063e-16	-0.0008	-0.00016	0.0004	0.00051284
60	1.0567e-12	1.0605e-12	1.0637e-12	2.7923e-15	1.0554e-12	1.0599e-12	1.0636e-12	2.9677e-15	-0.0017	-0.0006	0.0008	0.00098995
100	1.0586e-12	1.0609e-12	1.0649e-12	2.7797e-15	1.0583e-12	1.0611e-12	1.0639e-12	2.6461e-15	-0.001	0.00024	0.0018	0.0012341
110	1.0577e-12	1.06e-12	1.0642e-12	2.7179e-15	1.0567e-12	1.0591e-12	1.0612e-12	2.1487e-15	-0.003	-0.00086	0.0027	0.0021686

st: 30.19 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_FALLIN





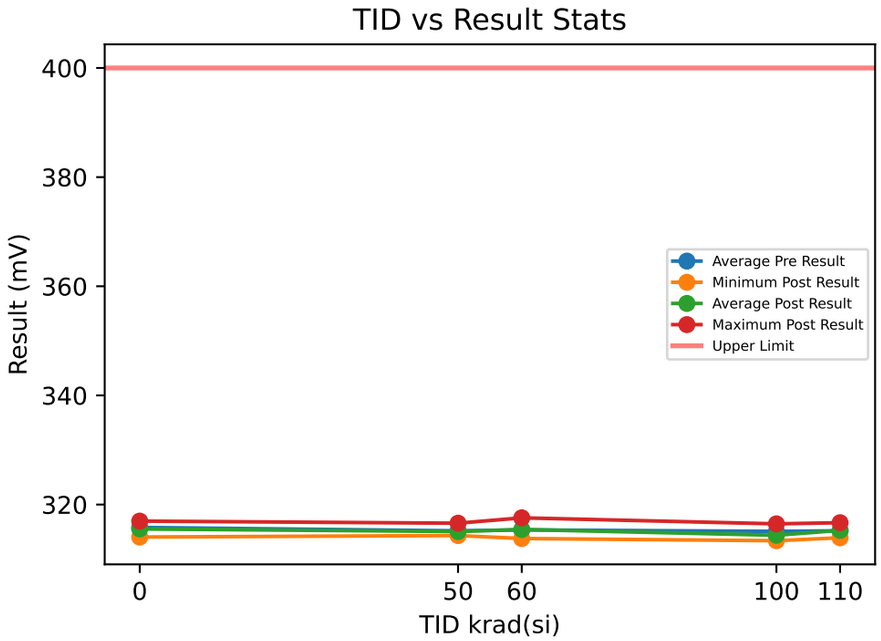
Test Results (No Limits Specified (%))

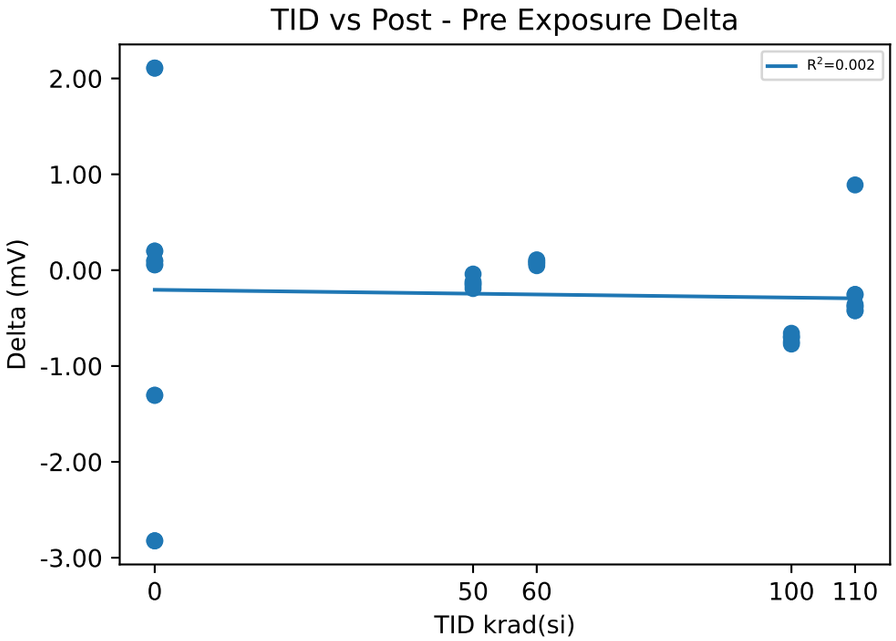
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0611e-12	1.0617e-12	0.0006
2	0	CU2	1.0596e-12	1.0595e-12	-0.0001
3	0	CU3	1.0576e-12	1.0572e-12	-0.0004
11	50	Unbiased-50k	1.0606e-12	1.0586e-12	-0.002
12	50	Unbiased-50k	1.0654e-12	1.0653e-12	-0.0001
13	50	Unbiased-50k	1.0591e-12	1.0595e-12	0.0004
14	50	Unbiased-50k	1.0579e-12	1.0574e-12	-0.0005
16	50	Unbiased-50k	1.0638e-12	1.063e-12	-0.0008
17	60	Biased-50k	1.0608e-12	1.0594e-12	-0.0014
18	60	Biased-50k	1.063e-12	1.0614e-12	-0.0016
19	60	Biased-50k	1.062e-12	1.0613e-12	-0.0007
20	60	Biased-50k	1.0604e-12	1.0595e-12	-0.0009
21	60	Biased-50k	1.0616e-12	1.0609e-12	-0.0007
24	100	Unbiased-100k	1.0595e-12	1.0588e-12	-0.0007
25	100	Unbiased-100k	1.0631e-12	1.0636e-12	0.0005
26	100	Unbiased-100k	1.0638e-12	1.0627e-12	-0.0011
27	100	Unbiased-100k	1.0621e-12	1.0626e-12	0.0005
28	100	Unbiased-100k	1.062e-12	1.0613e-12	-0.0007
29	110	Biased-100k	1.0612e-12	1.0591e-12	-0.0021
30	110	Biased-100k	1.0564e-12	1.0571e-12	0.0007
31	110	Biased-100k	1.059e-12	1.0571e-12	-0.0019
32	110	Biased-100k	1.0587e-12	1.0584e-12	-0.0003
34	110	Biased-100k	1.0589e-12	1.0576e-12	-0.0013

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0576e-12	1.0594e-12	1.0611e-12	1.7559e-15	1.0572e-12	1.0595e-12	1.0617e-12	2.2502e-15	-0.0004	3.3333e-05	0.0006	0.00051316
50	1.0579e-12	1.0614e-12	1.0654e-12	3.1596e-15	1.0574e-12	1.0608e-12	1.0653e-12	3.2853e-15	-0.002	-0.0006	0.0004	0.00090277
60	1.0604e-12	1.0616e-12	1.063e-12	1.0237e-15	1.0594e-12	1.0605e-12	1.0614e-12	9.7724e-16	-0.0016	-0.00106	-0.0007	0.00041593
100	1.0595e-12	1.0621e-12	1.0638e-12	1.6325e-15	1.0588e-12	1.0618e-12	1.0636e-12	1.8668e-15	-0.0011	-0.0003	0.0005	0.00074833
110	1.0564e-12	1.0588e-12	1.0612e-12	1.7009e-15	1.0571e-12	1.0579e-12	1.0591e-12	8.735e-16	-0.0021	-0.00098	0.0007	0.0011713

Device Test: 30.2 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD2/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





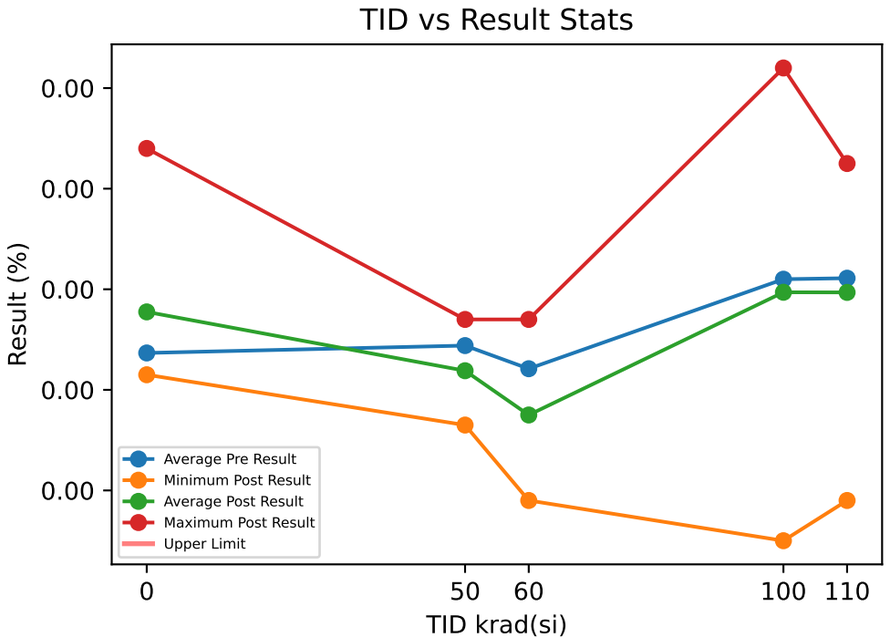
Test Results (Upper Limit = 400.0 (mV))

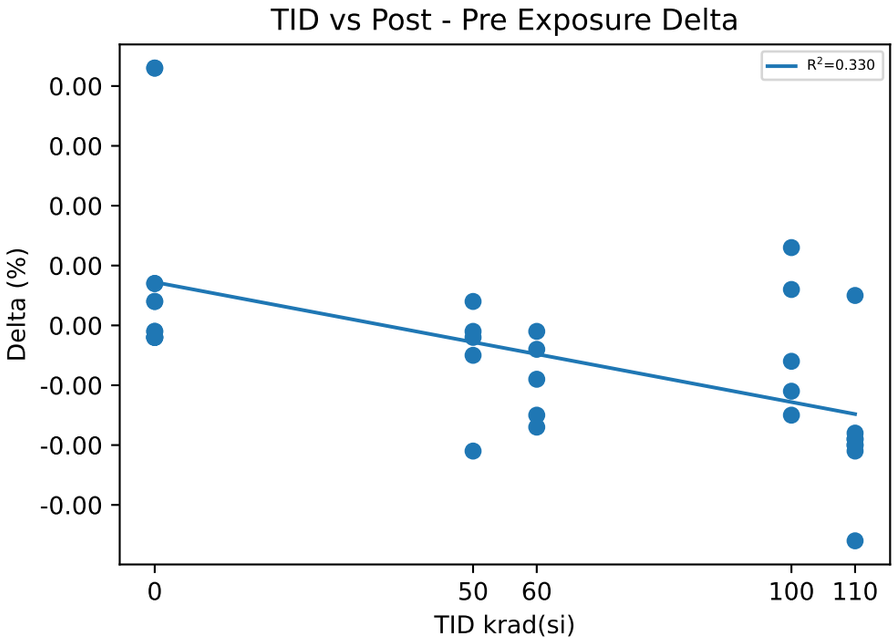
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	316.39	316.45	0.0561
2	0	CU2	314.16	314.36	0.1986
3	0	CU3	316.87	316.97	0.097
11	50	Unbiased-50k	315.07	314.91	-0.1571
12	50	Unbiased-50k	314.56	314.37	-0.1917
13	50	Unbiased-50k	314.46	314.32	-0.1386
14	50	Unbiased-50k	315.23	315.11	-0.1195
16	50	Unbiased-50k	316.62	316.58	-0.0406
17	60	Biased-50k	316.59	316.63	0.0468
18	60	Biased-50k	313.7	313.78	0.0796
19	60	Biased-50k	314.82	314.91	0.0959
20	60	Biased-50k	314.17	314.28	0.1079
21	60	Biased-50k	317.5	317.57	0.0693
24	100	Unbiased-100k	315.51	314.74	-0.7706
25	100	Unbiased-100k	314.08	313.37	-0.7022
26	100	Unbiased-100k	314.27	313.57	-0.6932
27	100	Unbiased-100k	314.48	313.73	-0.7466
28	100	Unbiased-100k	317.12	316.46	-0.6586
29	110	Biased-100k	314.36	314.01	-0.3568
30	110	Biased-100k	317.06	316.67	-0.3842
31	110	Biased-100k	315.6	315.23	-0.375
32	110	Biased-100k	313.03	313.92	0.8891
34	110	Biased-100k	315.92	315.5	-0.4223

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	314.16	315.81	316.87	1.4467	314.36	315.92	316.97	1.3809	0.0561	0.11723	0.1986	0.073373
50	314.46	315.19	316.62	0.8659	314.32	315.06	316.58	0.91729	-0.1917	-0.1295	-0.0406	0.056384
60	313.7	315.35	317.5	1.6238	313.78	315.43	317.57	1.6077	0.0468	0.0799	0.1079	0.023707
100	314.08	315.09	317.12	1.264	313.37	314.38	316.46	1.2804	-0.7706	-0.71424	-0.6586	0.044461
110	313.03	315.19	317.06	1.5461	313.92	315.06	316.67	1.1452	-0.4223	-0.12984	0.8891	0.57011

st: 30.20 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_FALLIN





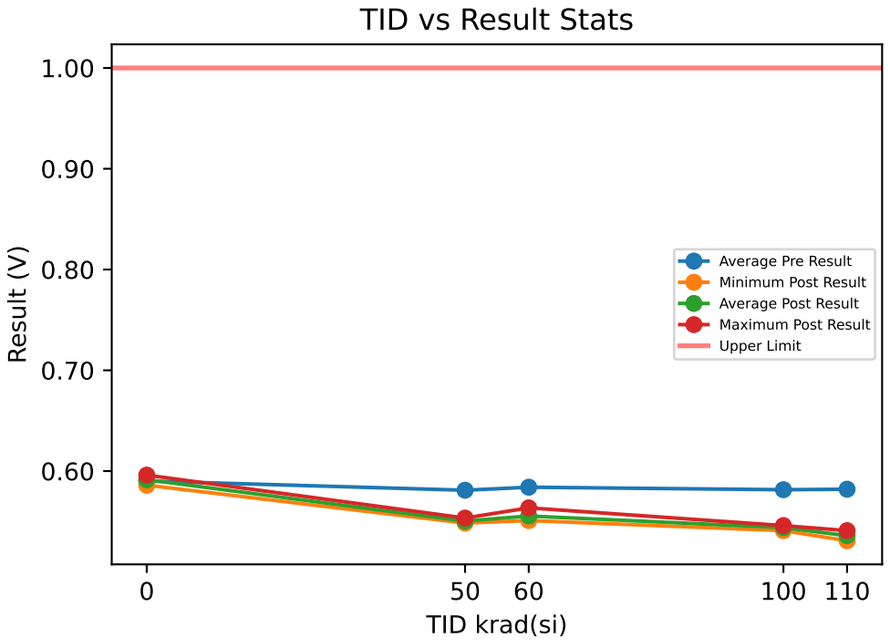
Test Results (No Limits Specified (%))

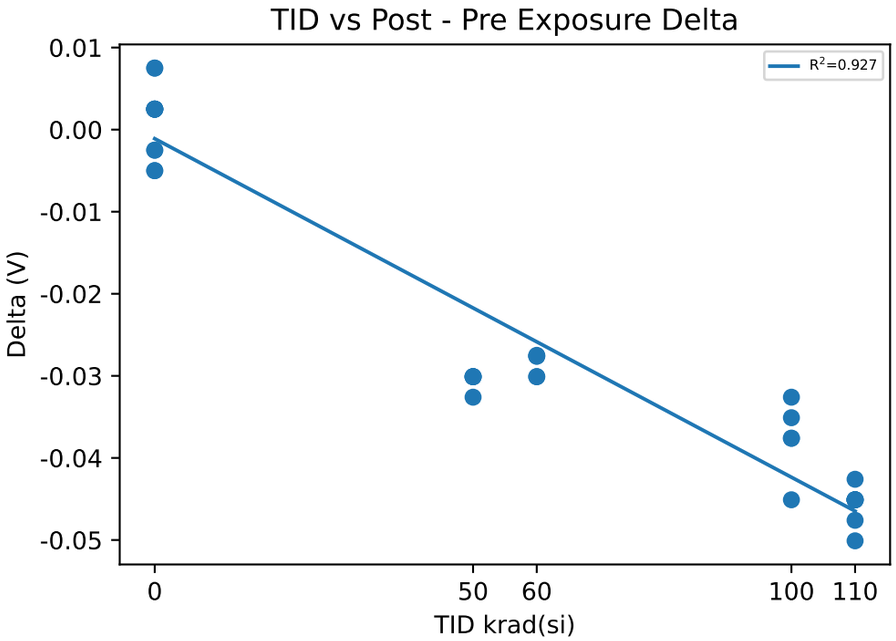
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0605e-12	1.0603e-12	-0.0002
2	0	CU2	1.0613e-12	1.0611e-12	-0.0002
3	0	CU3	1.0604e-12	1.0608e-12	0.0004
11	50	Unbiased-50k	1.0626e-12	1.0605e-12	-0.0021
12	50	Unbiased-50k	1.0595e-12	1.0593e-12	-0.0002
13	50	Unbiased-50k	1.061e-12	1.0614e-12	0.0004
14	50	Unbiased-50k	1.0614e-12	1.0609e-12	-0.0005
16	50	Unbiased-50k	1.0599e-12	1.0598e-12	-0.0001
17	60	Biased-50k	1.0597e-12	1.0593e-12	-0.0004
18	60	Biased-50k	1.0608e-12	1.0591e-12	-0.0017
19	60	Biased-50k	1.0593e-12	1.0578e-12	-0.0015
20	60	Biased-50k	1.0608e-12	1.0599e-12	-0.0009
21	60	Biased-50k	1.0615e-12	1.0614e-12	-0.0001
24	100	Unbiased-100k	1.0624e-12	1.0609e-12	-0.0015
25	100	Unbiased-100k	1.0581e-12	1.057e-12	-0.0011
26	100	Unbiased-100k	1.0658e-12	1.0664e-12	0.0006
27	100	Unbiased-100k	1.0638e-12	1.0651e-12	0.0013
28	100	Unbiased-100k	1.0609e-12	1.0603e-12	-0.0006
29	110	Biased-100k	1.0599e-12	1.0578e-12	-0.0021
30	110	Biased-100k	1.0604e-12	1.0586e-12	-0.0018
31	110	Biased-100k	1.0626e-12	1.059e-12	-0.0036
32	110	Biased-100k	1.0618e-12	1.0623e-12	0.0005
34	110	Biased-100k	1.0664e-12	1.0644e-12	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0604e-12	1.0607e-12	1.0613e-12	4.9329e-16	1.0603e-12	1.0607e-12	1.0611e-12	4.0415e-16	-0.0002	0	0.0004	0.00034641
50	1.0595e-12	1.0609e-12	1.0626e-12	1.2357e-15	1.0593e-12	1.0604e-12	1.0614e-12	8.4083e-16	-0.0021	-0.0005	0.0004	0.00095131
60	1.0593e-12	1.0604e-12	1.0615e-12	8.9833e-16	1.0578e-12	1.0595e-12	1.0614e-12	1.3096e-15	-0.0017	-0.00092	-0.0001	0.00068702
100	1.0581e-12	1.0622e-12	1.0658e-12	2.918e-15	1.057e-12	1.0619e-12	1.0664e-12	3.8096e-15	-0.0015	-0.00026	0.0013	0.001176
110	1.0599e-12	1.0622e-12	1.0664e-12	2.5733e-15	1.0578e-12	1.0604e-12	1.0644e-12	2.8093e-15	-0.0036	-0.0018	0.0005	0.0014714

Test: 30.25 MIN_VIN_FOR_PWRGD_OUTPUT(MinVin|Valid/PWRGD1/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_O





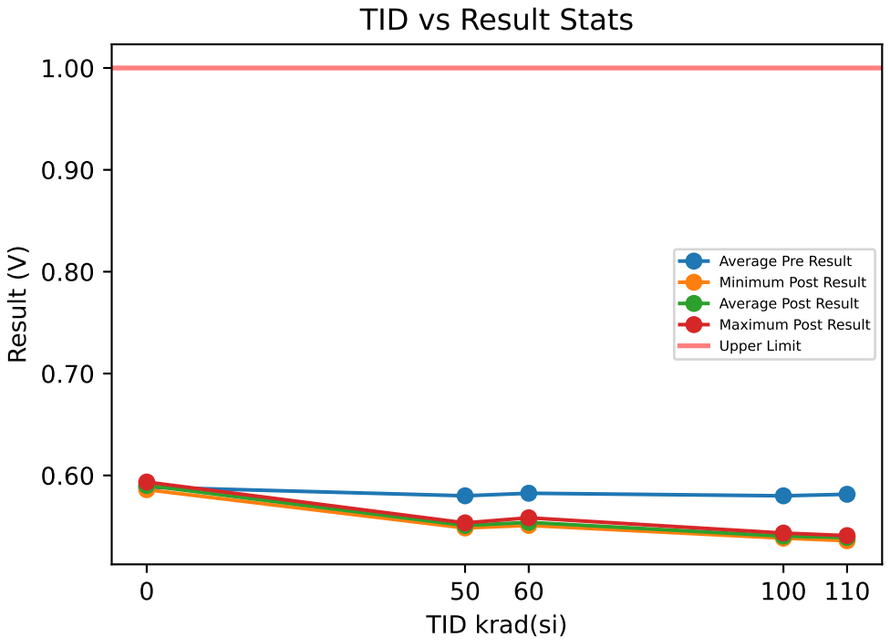
Test Results (Upper Limit = 1.0 (V))

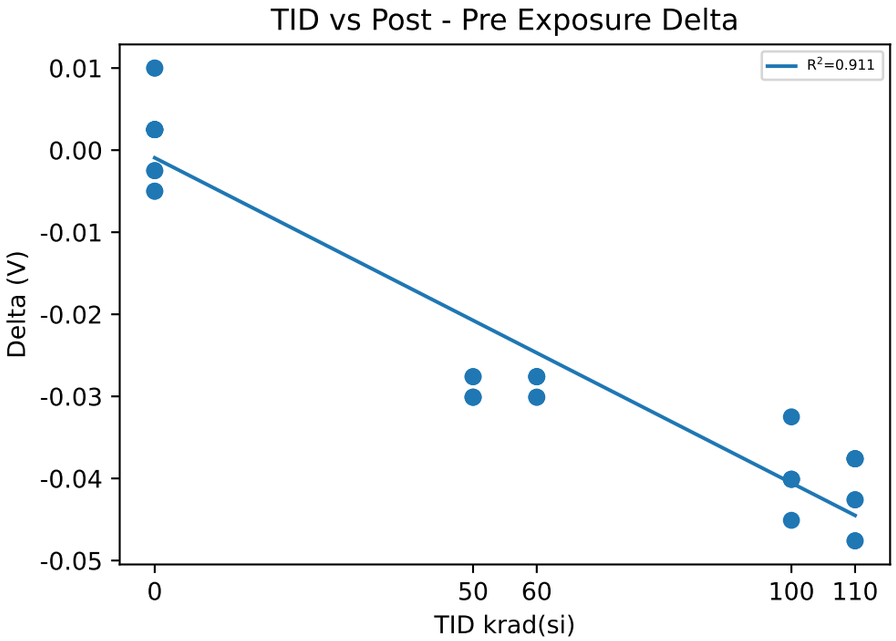
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.591	0.5935	0.0025
2	0	CU2	0.586	0.5885	0.0025
3	0	CU3	0.5935	0.596	0.0025
11	50	Unbiased-50k	0.5835	0.5534	-0.0301
12	50	Unbiased-50k	0.5785	0.5484	-0.0301
13	50	Unbiased-50k	0.581	0.5509	-0.0301
14	50	Unbiased-50k	0.5785	0.5484	-0.0301
16	50	Unbiased-50k	0.5835	0.5509	-0.0326
17	60	Biased-50k	0.5835	0.5559	-0.0276
18	60	Biased-50k	0.581	0.5534	-0.0276
19	60	Biased-50k	0.581	0.5509	-0.0301
20	60	Biased-50k	0.5835	0.5534	-0.0301
21	60	Biased-50k	0.591	0.5635	-0.0275
24	100	Unbiased-100k	0.581	0.5434	-0.0376
25	100	Unbiased-100k	0.5785	0.5459	-0.0326
26	100	Unbiased-100k	0.5785	0.5409	-0.0376
27	100	Unbiased-100k	0.581	0.5459	-0.0351
28	100	Unbiased-100k	0.5885	0.5434	-0.0451
29	110	Biased-100k	0.581	0.5359	-0.0451
30	110	Biased-100k	0.5885	0.5409	-0.0476
31	110	Biased-100k	0.581	0.5309	-0.0501
32	110	Biased-100k	0.5785	0.5359	-0.0426
34	110	Biased-100k	0.581	0.5359	-0.0451

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.586	0.59017	0.5935	0.0038188	0.5885	0.59267	0.596	0.0038188	0.0025	0.0025	0.0025	6.4161e-17
50	0.5785	0.581	0.5835	0.0025	0.5484	0.5504	0.5534	0.0020917	-0.0326	-0.0306	-0.0301	0.001118
60	0.581	0.584	0.591	0.0041079	0.5509	0.55542	0.5635	0.0048505	-0.0301	-0.02858	-0.0275	0.0013882
100	0.5785	0.5815	0.5885	0.0041079	0.5409	0.5439	0.5459	0.0020917	-0.0451	-0.0376	-0.0326	0.0046771
110	0.5785	0.582	0.5885	0.0037914	0.5309	0.5359	0.5409	0.0035355	-0.0501	-0.0461	-0.0426	0.0028504

Test: 30.26 MIN_VIN_FOR_PWRGD_OUTPUT(MinVin|Valid/PWRGD2/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_O





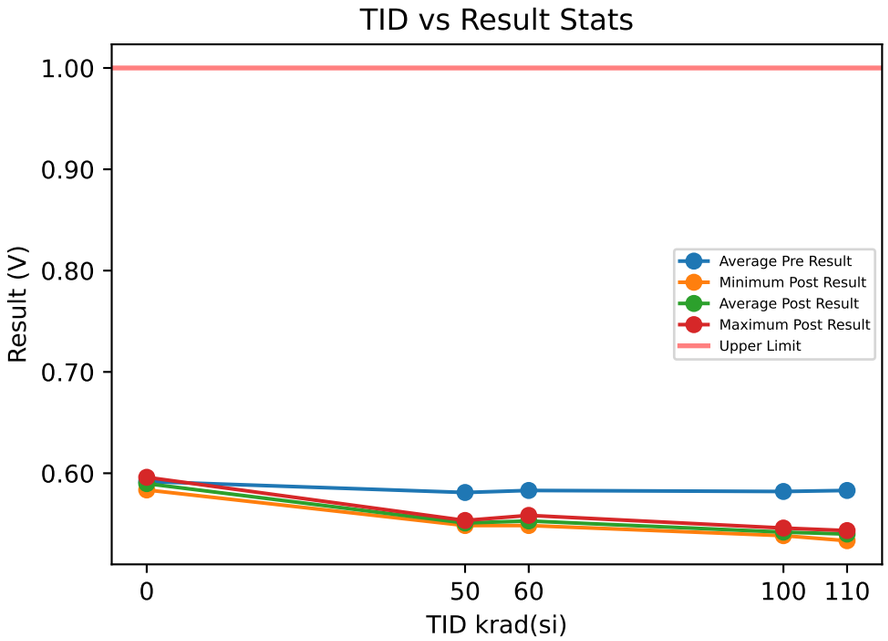
Test Results (Upper Limit = 1.0 (V))

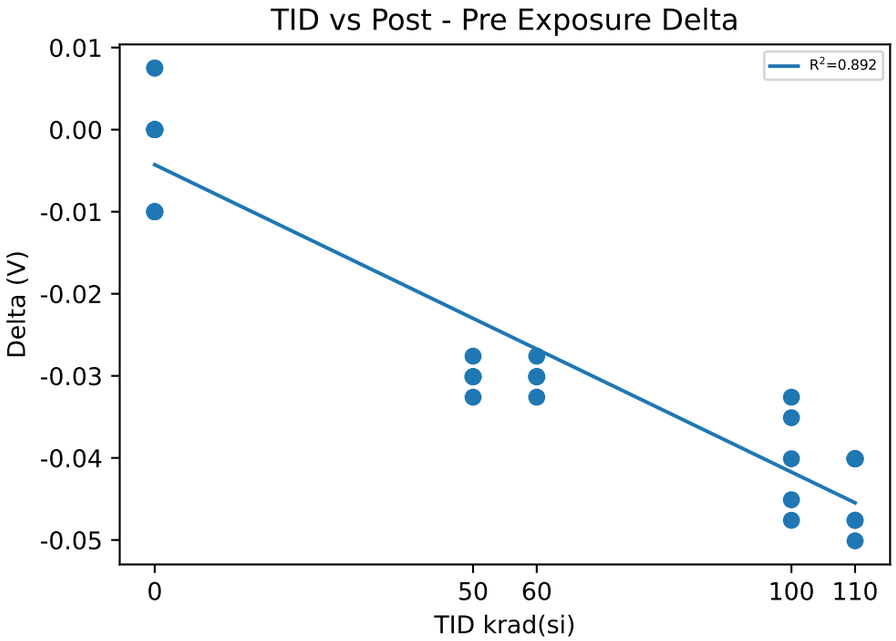
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.591	0.5935	0.0025
2	0	CU2	0.5835	0.586	0.0025
3	0	CU3	0.591	0.5935	0.0025
11	50	Unbiased-50k	0.581	0.5534	-0.0276
12	50	Unbiased-50k	0.581	0.5509	-0.0301
13	50	Unbiased-50k	0.5785	0.5509	-0.0276
14	50	Unbiased-50k	0.5785	0.5484	-0.0301
16	50	Unbiased-50k	0.581	0.5509	-0.0301
17	60	Biased-50k	0.5835	0.5559	-0.0276
18	60	Biased-50k	0.581	0.5534	-0.0276
19	60	Biased-50k	0.5785	0.5509	-0.0276
20	60	Biased-50k	0.581	0.5509	-0.0301
21	60	Biased-50k	0.5885	0.5584	-0.0301
24	100	Unbiased-100k	0.5835	0.5434	-0.0401
25	100	Unbiased-100k	0.5785	0.5384	-0.0401
26	100	Unbiased-100k	0.5759	0.5434	-0.0325
27	100	Unbiased-100k	0.5785	0.5384	-0.0401
28	100	Unbiased-100k	0.5835	0.5384	-0.0451
29	110	Biased-100k	0.5785	0.5359	-0.0426
30	110	Biased-100k	0.5885	0.5409	-0.0476
31	110	Biased-100k	0.5835	0.5359	-0.0476
32	110	Biased-100k	0.5785	0.5359	-0.0426
34	110	Biased-100k	0.5785	0.5409	-0.0376

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5835	0.5885	0.591	0.0043301	0.586	0.591	0.5935	0.0043301	0.0025	0.0025	0.0025	6.4067e-17
50	0.5785	0.58	0.581	0.0013693	0.5484	0.5509	0.5534	0.0017678	-0.0301	-0.0291	-0.0276	0.0013693
60	0.5785	0.5825	0.5885	0.0037914	0.5509	0.5539	0.5584	0.0032596	-0.0301	-0.0286	-0.0276	0.0013693
100	0.5759	0.57998	0.5835	0.0033841	0.5384	0.5404	0.5434	0.0027386	-0.0451	-0.03958	-0.0325	0.0045113
110	0.5785	0.5815	0.5885	0.0044721	0.5359	0.5379	0.5409	0.0027386	-0.0476	-0.0436	-0.0376	0.0041833

Test: 30.27 MIN_VIN_FOR_PWRGD_OUTPUT(MinVin|Valid/PWRGD3/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_O





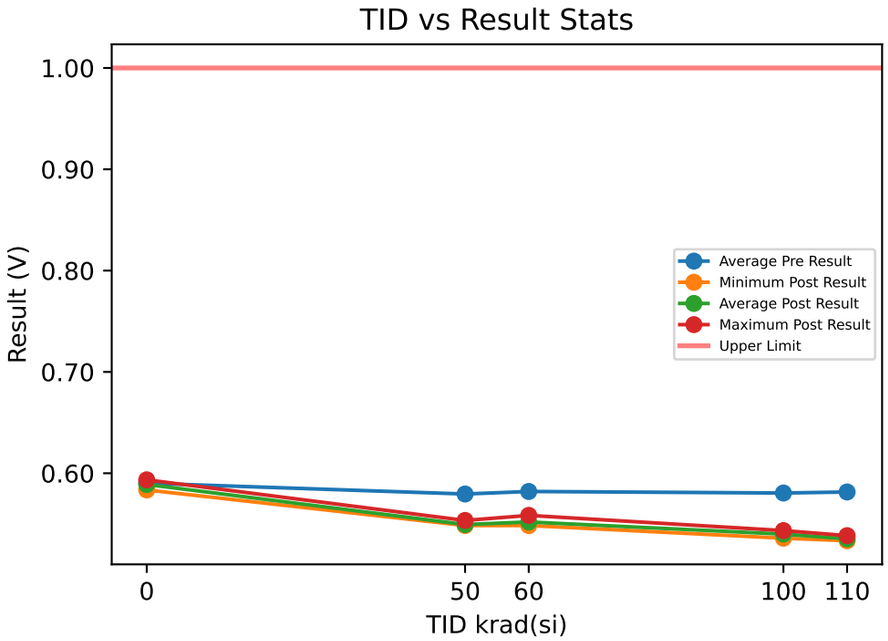
Test Results (Upper Limit = 1.0 (V))

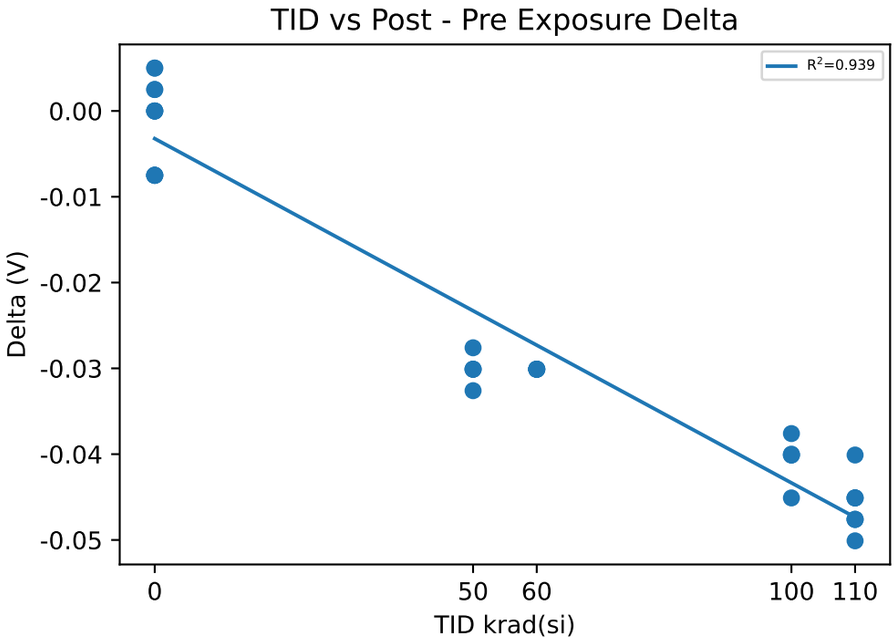
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.5935	0.5935	0
2	0	CU2	0.586	0.586	0
3	0	CU3	0.596	0.596	0
11	50	Unbiased-50k	0.581	0.5534	-0.0276
12	50	Unbiased-50k	0.581	0.5509	-0.0301
13	50	Unbiased-50k	0.5785	0.5484	-0.0301
14	50	Unbiased-50k	0.581	0.5509	-0.0301
16	50	Unbiased-50k	0.5835	0.5509	-0.0326
17	60	Biased-50k	0.5835	0.5534	-0.0301
18	60	Biased-50k	0.581	0.5534	-0.0276
19	60	Biased-50k	0.5785	0.5484	-0.0301
20	60	Biased-50k	0.5835	0.5509	-0.0326
21	60	Biased-50k	0.5885	0.5584	-0.0301
24	100	Unbiased-100k	0.5835	0.5384	-0.0451
25	100	Unbiased-100k	0.5785	0.5459	-0.0326
26	100	Unbiased-100k	0.5785	0.5434	-0.0351
27	100	Unbiased-100k	0.581	0.5409	-0.0401
28	100	Unbiased-100k	0.5885	0.5409	-0.0476
29	110	Biased-100k	0.5835	0.5334	-0.0501
30	110	Biased-100k	0.586	0.5384	-0.0476
31	110	Biased-100k	0.581	0.5334	-0.0476
32	110	Biased-100k	0.581	0.5409	-0.0401
34	110	Biased-100k	0.5835	0.5434	-0.0401

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.586	0.59183	0.596	0.0052042	0.586	0.59183	0.596	0.0052042	0	0	0	0
50	0.5785	0.581	0.5835	0.0017678	0.5484	0.5509	0.5534	0.0017678	-0.0326	-0.0301	-0.0276	0.0017678
60	0.5785	0.583	0.5885	0.0037081	0.5484	0.5529	0.5584	0.0037081	-0.0326	-0.0301	-0.0276	0.0017678
100	0.5785	0.582	0.5885	0.0041833	0.5384	0.5419	0.5459	0.0028504	-0.0476	-0.0401	-0.0326	0.0063738
110	0.581	0.583	0.586	0.0020917	0.5334	0.5379	0.5434	0.0044721	-0.0501	-0.0451	-0.0401	0.0046771

Test: 30.28 MIN_VIN_FOR_PWRGD_OUTPUT(MinVin|Valid/PWRGD4/3/3///90.9/634//1.8///@MIN_VIN_FOR_PWRGD_O





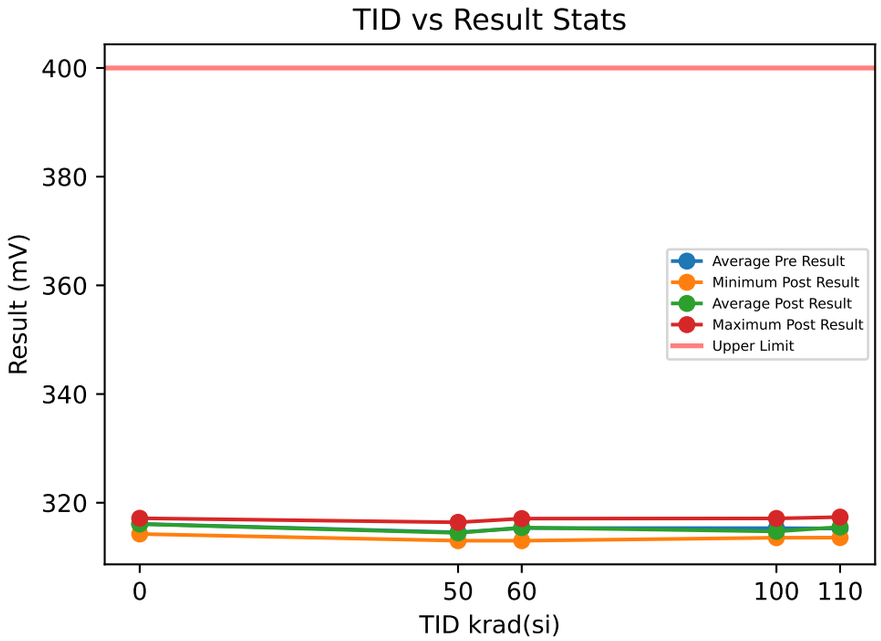
Test Results (Upper Limit = 1.0 (V))

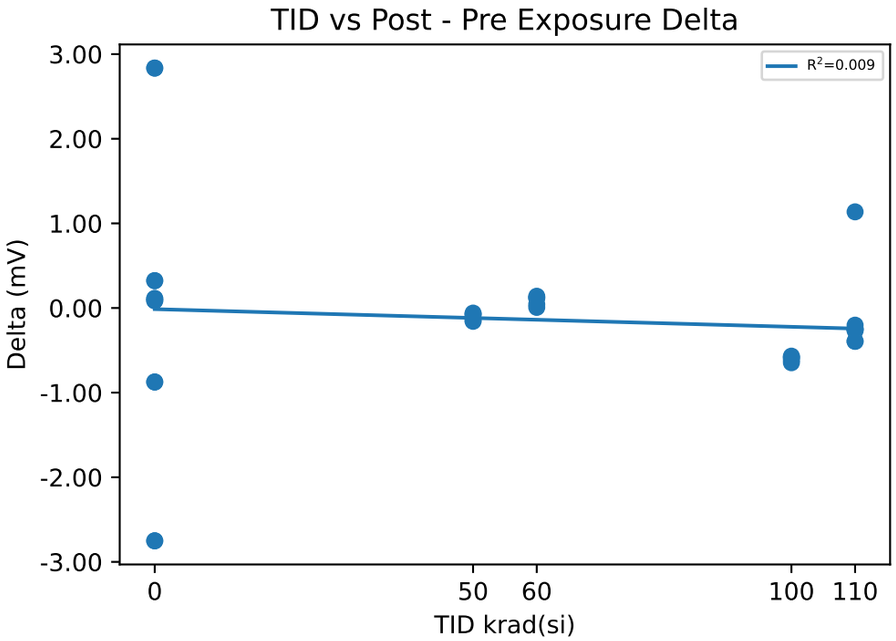
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.591	0.5935	0.0025
2	0	CU2	0.586	0.586	0
3	0	CU3	0.5935	0.5935	0
11	50	Unbiased-50k	0.581	0.5534	-0.0276
12	50	Unbiased-50k	0.5785	0.5484	-0.0301
13	50	Unbiased-50k	0.5785	0.5484	-0.0301
14	50	Unbiased-50k	0.5785	0.5484	-0.0301
16	50	Unbiased-50k	0.581	0.5484	-0.0326
17	60	Biased-50k	0.5835	0.5534	-0.0301
18	60	Biased-50k	0.5785	0.5484	-0.0301
19	60	Biased-50k	0.5785	0.5484	-0.0301
20	60	Biased-50k	0.581	0.5509	-0.0301
21	60	Biased-50k	0.5885	0.5584	-0.0301
24	100	Unbiased-100k	0.5835	0.5434	-0.0401
25	100	Unbiased-100k	0.5785	0.5409	-0.0376
26	100	Unbiased-100k	0.5759	0.5359	-0.04
27	100	Unbiased-100k	0.5785	0.5384	-0.0401
28	100	Unbiased-100k	0.586	0.5409	-0.0451
29	110	Biased-100k	0.581	0.5334	-0.0476
30	110	Biased-100k	0.586	0.5359	-0.0501
31	110	Biased-100k	0.581	0.5359	-0.0451
32	110	Biased-100k	0.5785	0.5384	-0.0401
34	110	Biased-100k	0.581	0.5359	-0.0451

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.586	0.59017	0.5935	0.0038188	0.586	0.591	0.5935	0.0043301	0	0.00083333	0.0025	0.0014434
50	0.5785	0.5795	0.581	0.0013693	0.5484	0.5494	0.5534	0.0022361	-0.0326	-0.0301	-0.0276	0.0017678
60	0.5785	0.582	0.5885	0.0041833	0.5484	0.5519	0.5584	0.0041833	-0.0301	-0.0301	-0.0301	0
100	0.5759	0.58048	0.586	0.0041355	0.5359	0.5399	0.5434	0.0028504	-0.0451	-0.04058	-0.0376	0.0027435
110	0.5785	0.5815	0.586	0.0027386	0.5334	0.5359	0.5384	0.0017678	-0.0501	-0.0456	-0.0401	0.0037081

Device Test: 30.3 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD3/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





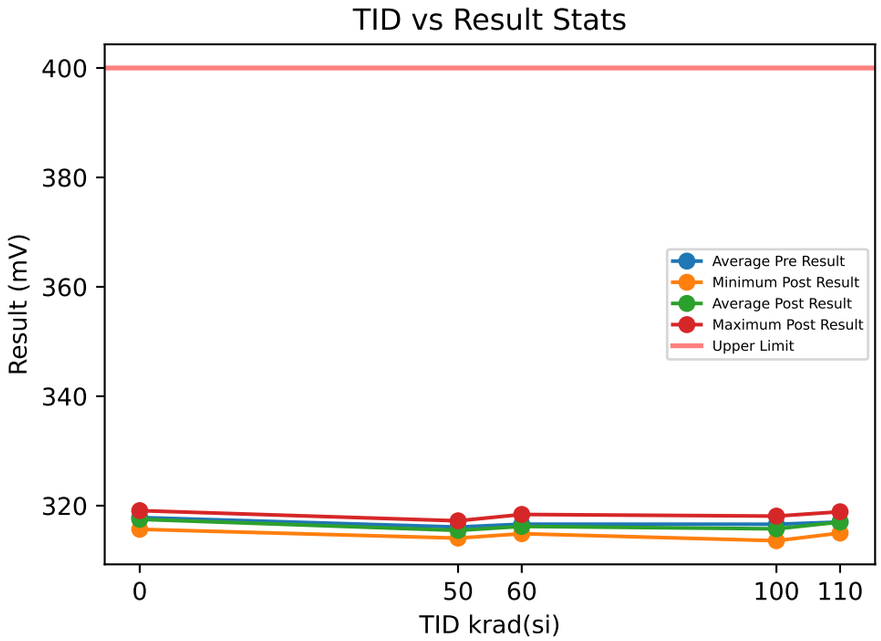
Test Results (Upper Limit = 400.0 (mV))

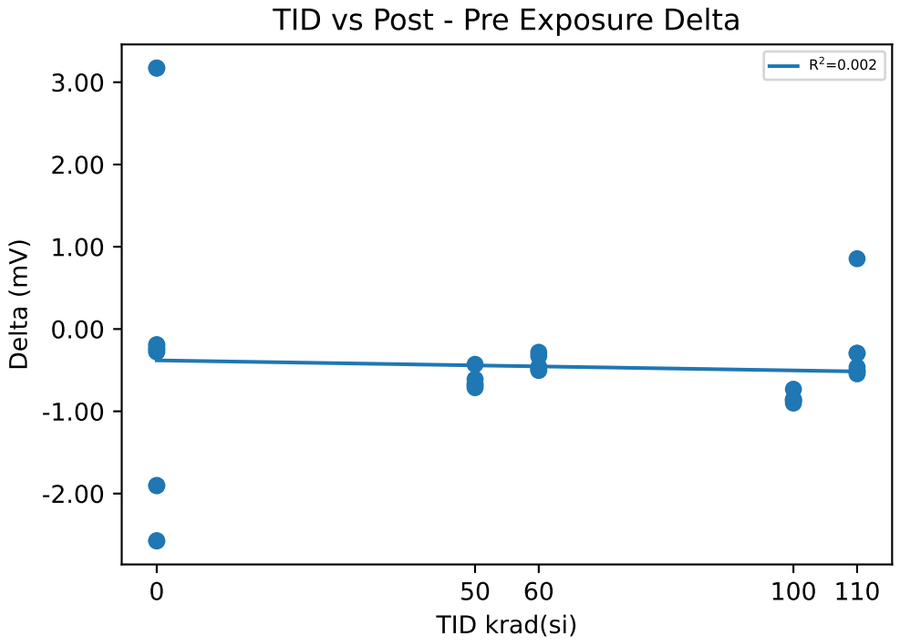
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	317.06	317.14	0.0869
2	0	CU2	314.28	314.61	0.323
3	0	CU3	317	317.11	0.1118
11	50	Unbiased-50k	314.05	313.91	-0.1466
12	50	Unbiased-50k	313.17	313.01	-0.1575
13	50	Unbiased-50k	313.42	313.36	-0.0601
14	50	Unbiased-50k	315.64	315.56	-0.0782
16	50	Unbiased-50k	316.47	316.4	-0.0737
17	60	Biased-50k	316.35	316.36	0.0074
18	60	Biased-50k	312.87	313.01	0.1391
19	60	Biased-50k	316.23	316.35	0.123
20	60	Biased-50k	314.21	314.32	0.1164
21	60	Biased-50k	317.04	317.08	0.043
24	100	Unbiased-100k	315.12	314.51	-0.6185
25	100	Unbiased-100k	314.13	313.56	-0.5688
26	100	Unbiased-100k	314.65	314.01	-0.6467
27	100	Unbiased-100k	315.01	314.43	-0.5811
28	100	Unbiased-100k	317.7	317.11	-0.5899
29	110	Biased-100k	314.81	314.54	-0.2688
30	110	Biased-100k	317.56	317.36	-0.2027
31	110	Biased-100k	313.83	313.58	-0.2472
32	110	Biased-100k	313.87	315.01	1.1364
34	110	Biased-100k	316.24	315.85	-0.3934

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	314.28	316.11	317.06	1.5848	314.61	316.29	317.14	1.4556	0.0869	0.1739	0.323	0.12972
50	313.17	314.55	316.47	1.4401	313.01	314.45	316.4	1.4634	-0.1575	-0.10322	-0.0601	0.045235
60	312.87	315.34	317.04	1.7371	313.01	315.42	317.08	1.6965	0.0074	0.08578	0.1391	0.057314
100	314.13	315.32	317.7	1.3851	313.56	314.72	317.11	1.3883	-0.6467	-0.601	-0.5688	0.031428
110	313.83	315.26	317.56	1.614	313.58	315.27	317.36	1.4255	-0.3934	0.00486	1.1364	0.63649

Device Test: 30.4 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD4/3/3///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





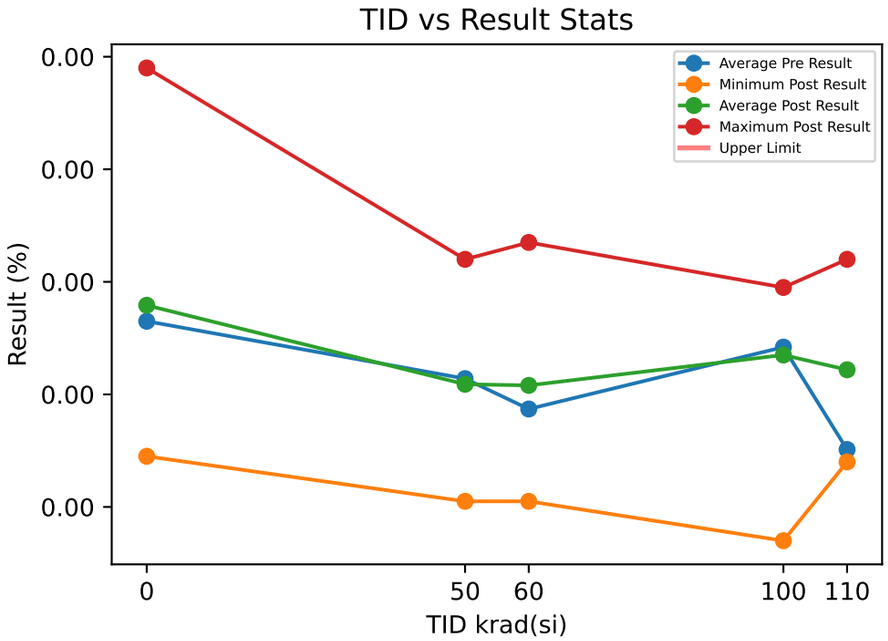
Test Results (Upper Limit = 400.0 (mV))

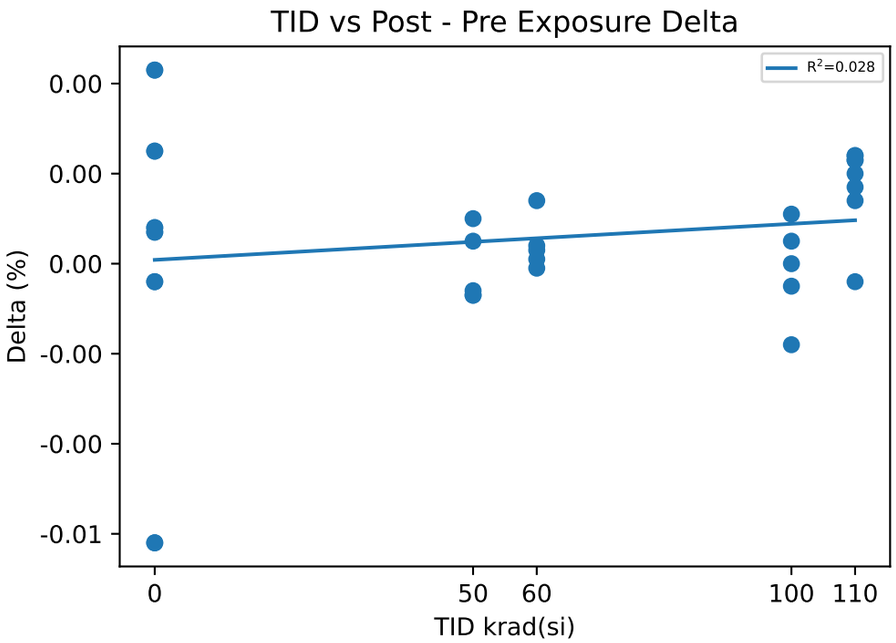
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	319.32	319.04	-0.2758
2	0	CU2	315.92	315.68	-0.2383
3	0	CU3	318.27	318.08	-0.1915
11	50	Unbiased-50k	315.53	314.82	-0.7129
12	50	Unbiased-50k	314.75	314.07	-0.6817
13	50	Unbiased-50k	316.02	315.35	-0.6661
14	50	Unbiased-50k	316.52	315.91	-0.6099
16	50	Unbiased-50k	317.66	317.23	-0.4288
17	60	Biased-50k	317.13	316.63	-0.5038
18	60	Biased-50k	315.34	314.88	-0.4599
19	60	Biased-50k	316.62	316.13	-0.4881
20	60	Biased-50k	315.33	315	-0.3288
21	60	Biased-50k	318.68	318.39	-0.2821
24	100	Unbiased-100k	316.52	315.66	-0.8598
25	100	Unbiased-100k	314.46	313.6	-0.869
26	100	Unbiased-100k	316.27	315.37	-0.9003
27	100	Unbiased-100k	316.95	316.1	-0.8565
28	100	Unbiased-100k	318.83	318.1	-0.7316
29	110	Biased-100k	317.18	316.72	-0.463
30	110	Biased-100k	319.4	318.89	-0.5099
31	110	Biased-100k	315.54	315	-0.5443
32	110	Biased-100k	315.19	316.05	0.8548
34	110	Biased-100k	317.75	317.23	-0.5162

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	315.92	317.84	319.32	1.7388	315.68	317.6	319.04	1.7292	-0.2758	-0.2352	-0.1915	0.042235
50	314.75	316.1	317.66	1.0908	314.07	315.48	317.23	1.1933	-0.7129	-0.61988	-0.4288	0.11316
60	315.33	316.62	318.68	1.3961	314.88	316.21	318.39	1.4304	-0.5038	-0.41254	-0.2821	0.10038
100	314.46	316.61	318.83	1.562	313.6	315.76	318.1	1.6136	-0.9003	-0.84344	-0.7316	0.064871
110	315.19	317.01	319.4	1.7112	315	316.78	318.89	1.4448	-0.5443	-0.23572	0.8548	0.61032

Test: 30.5 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING





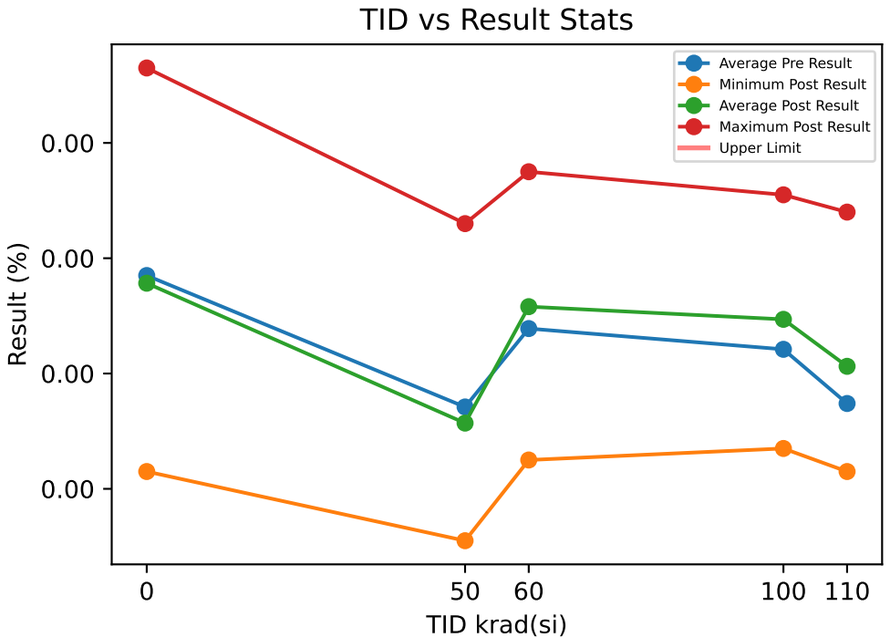
Test Results (No Limits Specified (%))

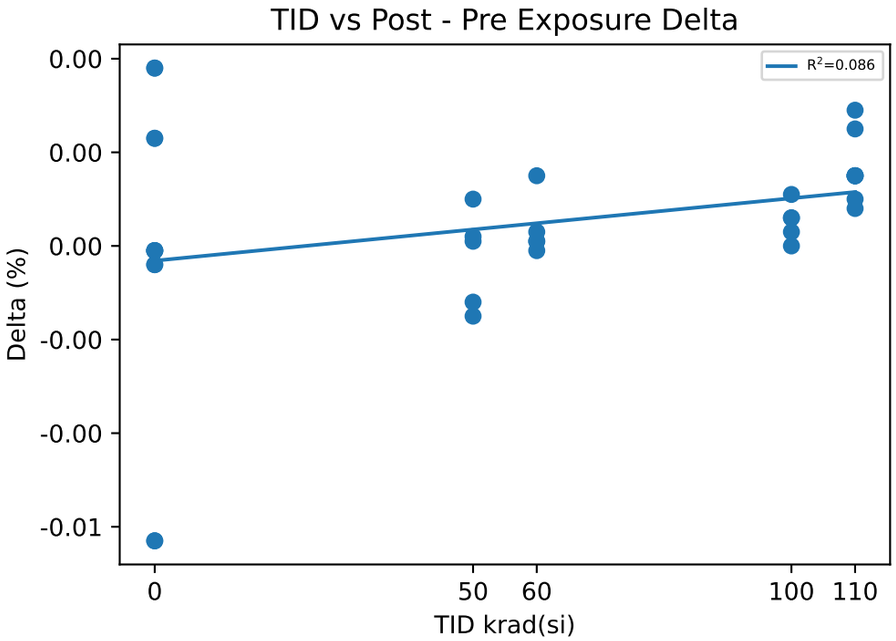
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.061e-13	9.069e-13	0.0008
2	0	CU2	9.131e-13	9.138e-13	0.0007
3	0	CU3	9.087e-13	9.083e-13	-0.0004
11	50	Unbiased-50k	9.094e-13	9.104e-13	0.001
12	50	Unbiased-50k	9.067e-13	9.061e-13	-0.0006
13	50	Unbiased-50k	9.088e-13	9.081e-13	-0.0007
14	50	Unbiased-50k	9.091e-13	9.084e-13	-0.0007
16	50	Unbiased-50k	9.074e-13	9.079e-13	0.0005
17	60	Biased-50k	9.083e-13	9.082e-13	-0.0001
18	60	Biased-50k	9.072e-13	9.075e-13	0.0003
19	60	Biased-50k	9.079e-13	9.083e-13	0.0004
20	60	Biased-50k	9.06e-13	9.061e-13	0.0001
21	60	Biased-50k	9.093e-13	9.107e-13	0.0014
24	100	Unbiased-100k	9.072e-13	9.054e-13	-0.0018
25	100	Unbiased-100k	9.095e-13	9.09e-13	-0.0005
26	100	Unbiased-100k	9.088e-13	9.099e-13	0.0011
27	100	Unbiased-100k	9.092e-13	9.097e-13	0.0005
28	100	Unbiased-100k	9.095e-13	9.095e-13	0
29	110	Biased-100k	9.06e-13	9.074e-13	0.0014
30	110	Biased-100k	9.108e-13	9.104e-13	-0.0004
31	110	Biased-100k	9.074e-13	9.091e-13	0.0017
32	110	Biased-100k	9.048e-13	9.068e-13	0.002
34	110	Biased-100k	9.061e-13	9.084e-13	0.0023

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.061e-13	9.093e-13	9.131e-13	3.5384e-15	9.069e-13	9.0967e-13	9.138e-13	3.6474e-15	-0.0004	0.00036667	0.0008	0.00066583
50	9.067e-13	9.0828e-13	9.094e-13	1.1692e-15	9.061e-13	9.0818e-13	9.104e-13	1.532e-15	-0.0007	-0.0001	0.001	0.00079687
60	9.06e-13	9.0774e-13	9.093e-13	1.2341e-15	9.061e-13	9.0816e-13	9.107e-13	1.6697e-15	-0.0001	0.00042	0.0014	0.00058052
100	9.072e-13	9.0884e-13	9.095e-13	9.6073e-16	9.054e-13	9.087e-13	9.099e-13	1.8748e-15	-0.0018	-0.00014	0.0011	0.0011014
110	9.048e-13	9.0702e-13	9.108e-13	2.3048e-15	9.068e-13	9.0842e-13	9.104e-13	1.4184e-15	-0.0004	0.0014	0.0023	0.0010607

Test: 30.6 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD2/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING





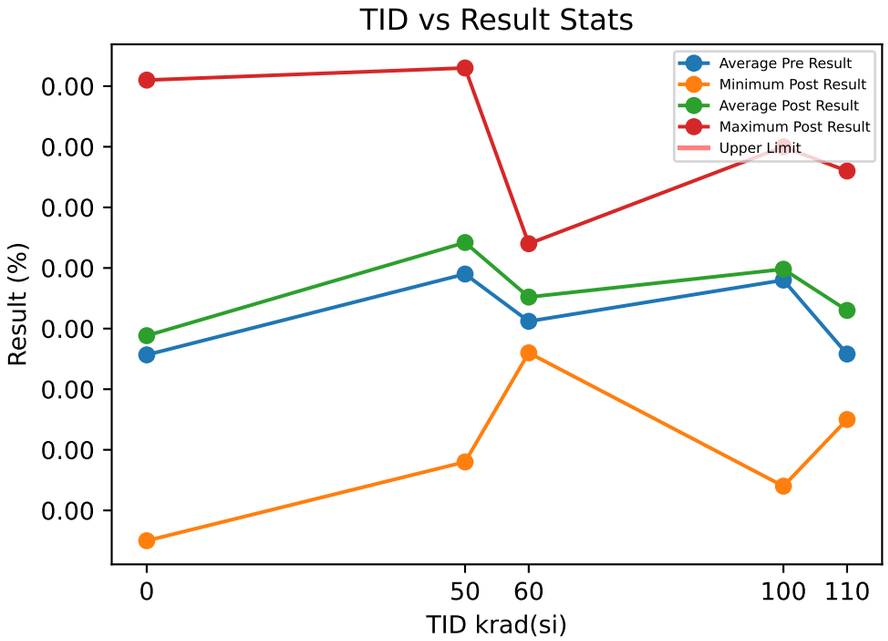
Test Results (No Limits Specified (%))

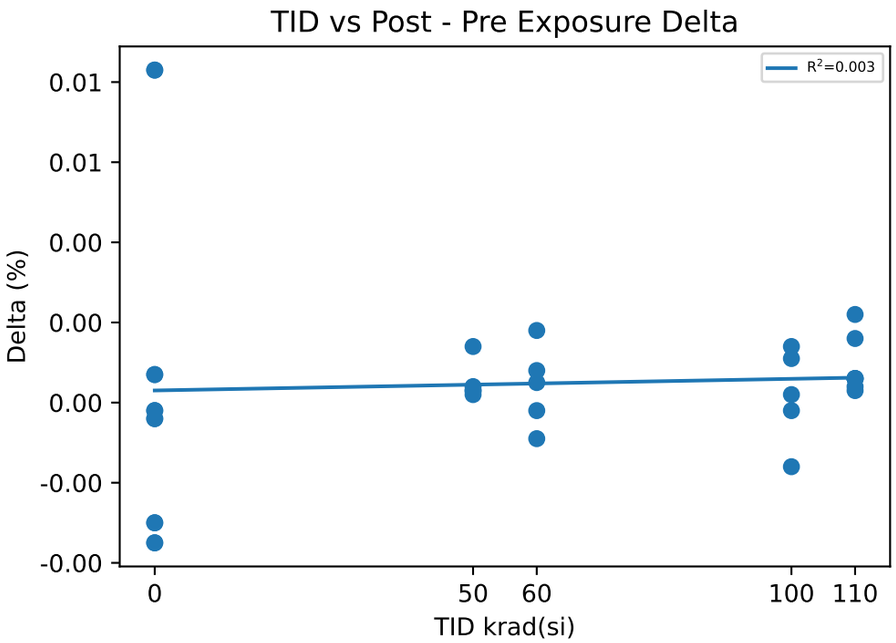
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.126e-13	9.125e-13	-0.0001
2	0	CU2	9.095e-13	9.094e-13	-0.0001
3	0	CU3	9.07e-13	9.066e-13	-0.0004
11	50	Unbiased-50k	9.096e-13	9.106e-13	0.001
12	50	Unbiased-50k	9.06e-13	9.062e-13	0.0002
13	50	Unbiased-50k	9.081e-13	9.066e-13	-0.0015
14	50	Unbiased-50k	9.071e-13	9.072e-13	0.0001
16	50	Unbiased-50k	9.063e-13	9.051e-13	-0.0012
17	60	Biased-50k	9.066e-13	9.065e-13	-0.0001
18	60	Biased-50k	9.097e-13	9.098e-13	0.0001
19	60	Biased-50k	9.064e-13	9.067e-13	0.0003
20	60	Biased-50k	9.112e-13	9.113e-13	0.0001
21	60	Biased-50k	9.1e-13	9.115e-13	0.0015
24	100	Unbiased-100k	9.072e-13	9.078e-13	0.0006
25	100	Unbiased-100k	9.1e-13	9.111e-13	0.0011
26	100	Unbiased-100k	9.105e-13	9.108e-13	0.0003
27	100	Unbiased-100k	9.077e-13	9.083e-13	0.0006
28	100	Unbiased-100k	9.067e-13	9.067e-13	0
29	110	Biased-100k	9.077e-13	9.106e-13	0.0029
30	110	Biased-100k	9.066e-13	9.076e-13	0.001
31	110	Biased-100k	9.1e-13	9.108e-13	0.0008
32	110	Biased-100k	9.083e-13	9.108e-13	0.0025
34	110	Biased-100k	9.048e-13	9.063e-13	0.0015

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.07e-13	9.097e-13	9.126e-13	2.8054e-15	9.066e-13	9.095e-13	9.125e-13	2.9513e-15	-0.0004	-0.0002	-0.0001	0.00017321
50	9.06e-13	9.0742e-13	9.096e-13	1.4653e-15	9.051e-13	9.0714e-13	9.106e-13	2.0804e-15	-0.0015	-0.00028	0.001	0.0010426
60	9.064e-13	9.0878e-13	9.112e-13	2.1568e-15	9.065e-13	9.0916e-13	9.115e-13	2.4286e-15	-0.0001	0.00038	0.0015	0.00064187
100	9.067e-13	9.0842e-13	9.105e-13	1.7167e-15	9.067e-13	9.0894e-13	9.111e-13	1.9269e-15	0	0.00052	0.0011	0.00040866
110	9.048e-13	9.0748e-13	9.1e-13	1.9383e-15	9.063e-13	9.0922e-13	9.108e-13	2.1241e-15	0.0008	0.00174	0.0029	0.00092358

Test: 30.7 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD3/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING





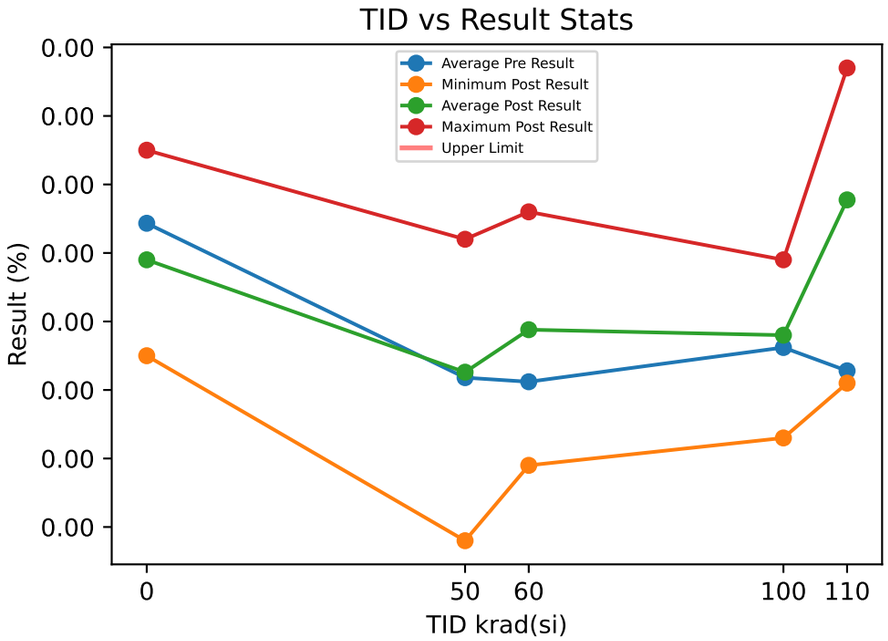
Test Results (No Limits Specified (%))

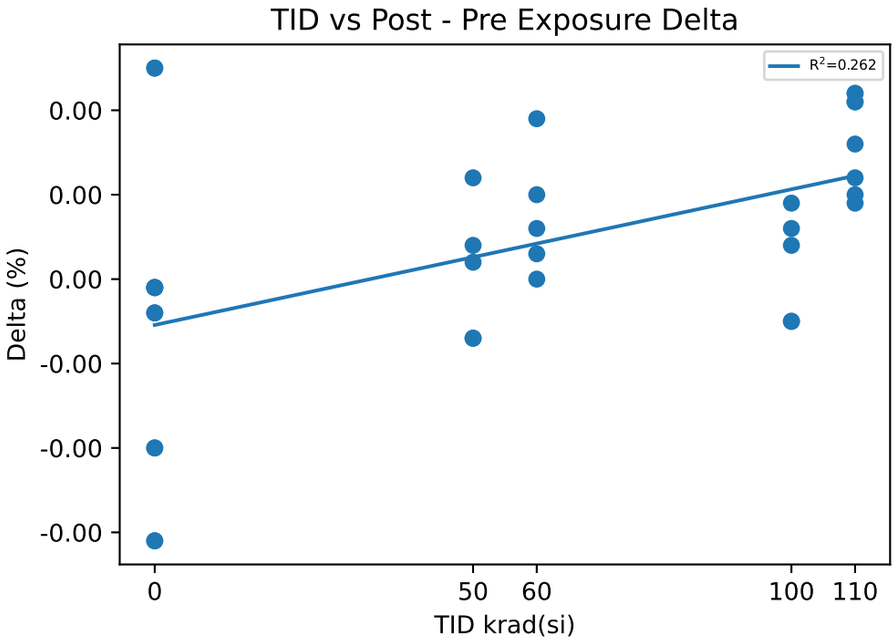
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.114e-13	9.112e-13	-0.0002
2	0	CU2	9.038e-13	9.045e-13	0.0007
3	0	CU3	9.075e-13	9.071e-13	-0.0004
11	50	Unbiased-50k	9.054e-13	9.058e-13	0.0004
12	50	Unbiased-50k	9.1e-13	9.103e-13	0.0003
13	50	Unbiased-50k	9.074e-13	9.077e-13	0.0003
14	50	Unbiased-50k	9.108e-13	9.11e-13	0.0002
16	50	Unbiased-50k	9.109e-13	9.123e-13	0.0014
17	60	Biased-50k	9.086e-13	9.094e-13	0.0008
18	60	Biased-50k	9.069e-13	9.087e-13	0.0018
19	60	Biased-50k	9.085e-13	9.09e-13	0.0005
20	60	Biased-50k	9.085e-13	9.076e-13	-0.0009
21	60	Biased-50k	9.081e-13	9.079e-13	-0.0002
24	100	Unbiased-100k	9.056e-13	9.054e-13	-0.0002
25	100	Unbiased-100k	9.099e-13	9.11e-13	0.0011
26	100	Unbiased-100k	9.087e-13	9.089e-13	0.0002
27	100	Unbiased-100k	9.085e-13	9.099e-13	0.0014
28	100	Unbiased-100k	9.113e-13	9.097e-13	-0.0016
29	110	Biased-100k	9.072e-13	9.094e-13	0.0022
30	110	Biased-100k	9.102e-13	9.106e-13	0.0004
31	110	Biased-100k	9.049e-13	9.065e-13	0.0016
32	110	Biased-100k	9.084e-13	9.087e-13	0.0003
34	110	Biased-100k	9.072e-13	9.078e-13	0.0006

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.038e-13	9.0757e-13	9.114e-13	3.8004e-15	9.045e-13	9.076e-13	9.112e-13	3.3779e-15	-0.0004	3.3333e-05	0.0007	0.00058595
50	9.054e-13	9.089e-13	9.109e-13	2.4145e-15	9.058e-13	9.0942e-13	9.123e-13	2.6281e-15	0.0002	0.00052	0.0014	0.00049699
60	9.069e-13	9.0812e-13	9.086e-13	7.0852e-16	9.076e-13	9.0852e-13	9.094e-13	7.5299e-16	-0.0009	0.0004	0.0018	0.0010223
100	9.056e-13	9.088e-13	9.113e-13	2.1095e-15	9.054e-13	9.0898e-13	9.11e-13	2.1371e-15	-0.0016	0.00018	0.0014	0.0011883
110	9.049e-13	9.0758e-13	9.102e-13	1.937e-15	9.065e-13	9.086e-13	9.106e-13	1.5572e-15	0.0003	0.00102	0.0022	0.00083785

Test: 30.8 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD4/3/3///90.9/634//1.8///@VSENSE_VTH_FALLING





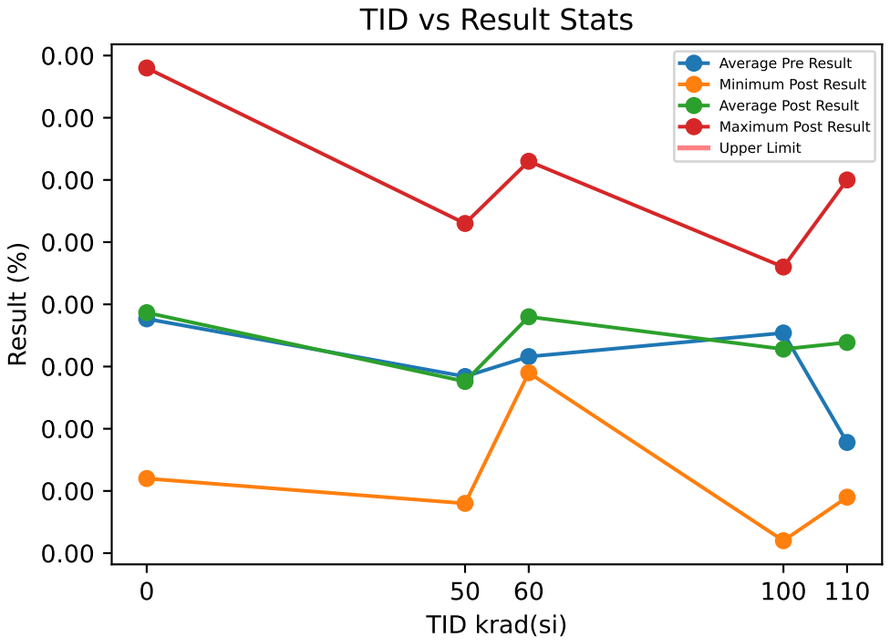
Test Results (No Limits Specified (%))

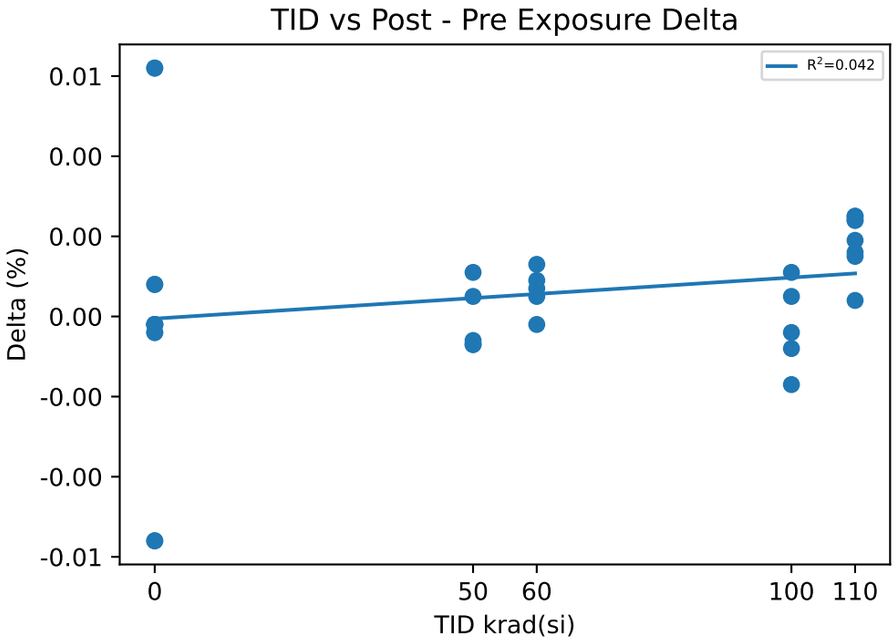
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.116e-13	9.115e-13	-0.0001
2	0	CU2	9.089e-13	9.088e-13	-0.0001
3	0	CU3	9.108e-13	9.104e-13	-0.0004
11	50	Unbiased-50k	9.066e-13	9.059e-13	-0.0007
12	50	Unbiased-50k	9.083e-13	9.095e-13	0.0012
13	50	Unbiased-50k	9.1e-13	9.102e-13	0.0002
14	50	Unbiased-50k	9.065e-13	9.058e-13	-0.0007
16	50	Unbiased-50k	9.095e-13	9.099e-13	0.0004
17	60	Biased-50k	9.087e-13	9.087e-13	0
18	60	Biased-50k	9.079e-13	9.098e-13	0.0019
19	60	Biased-50k	9.066e-13	9.069e-13	0.0003
20	60	Biased-50k	9.096e-13	9.106e-13	0.001
21	60	Biased-50k	9.078e-13	9.084e-13	0.0006
24	100	Unbiased-100k	9.067e-13	9.073e-13	0.0006
25	100	Unbiased-100k	9.087e-13	9.082e-13	-0.0005
26	100	Unbiased-100k	9.096e-13	9.091e-13	-0.0005
27	100	Unbiased-100k	9.095e-13	9.099e-13	0.0004
28	100	Unbiased-100k	9.086e-13	9.095e-13	0.0009
29	110	Biased-100k	9.078e-13	9.09e-13	0.0012
30	110	Biased-100k	9.075e-13	9.085e-13	0.001
31	110	Biased-100k	9.072e-13	9.081e-13	0.0009
32	110	Biased-100k	9.084e-13	9.1e-13	0.0016
34	110	Biased-100k	9.105e-13	9.126e-13	0.0021

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.089e-13	9.1043e-13	9.116e-13	1.3868e-15	9.088e-13	9.1023e-13	9.115e-13	1.3577e-15	-0.0004	-0.0002	-0.0001	0.00017321
50	9.065e-13	9.0818e-13	9.1e-13	1.6115e-15	9.058e-13	9.0826e-13	9.102e-13	2.2143e-15	-0.0007	8e-05	0.0012	0.00080436
60	9.066e-13	9.0812e-13	9.096e-13	1.1167e-15	9.069e-13	9.0888e-13	9.106e-13	1.4132e-15	0	0.00076	0.0019	0.00073689
100	9.067e-13	9.0862e-13	9.096e-13	1.1649e-15	9.073e-13	9.088e-13	9.099e-13	1.0488e-15	-0.0005	0.00018	0.0009	0.00064576
110	9.072e-13	9.0828e-13	9.105e-13	1.318e-15	9.081e-13	9.0964e-13	9.126e-13	1.8008e-15	0.0009	0.00136	0.0021	0.00049295

Test: 30.9 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD1/3/3///90.9/634//1.8///@VSENSE_VTH_RISING_





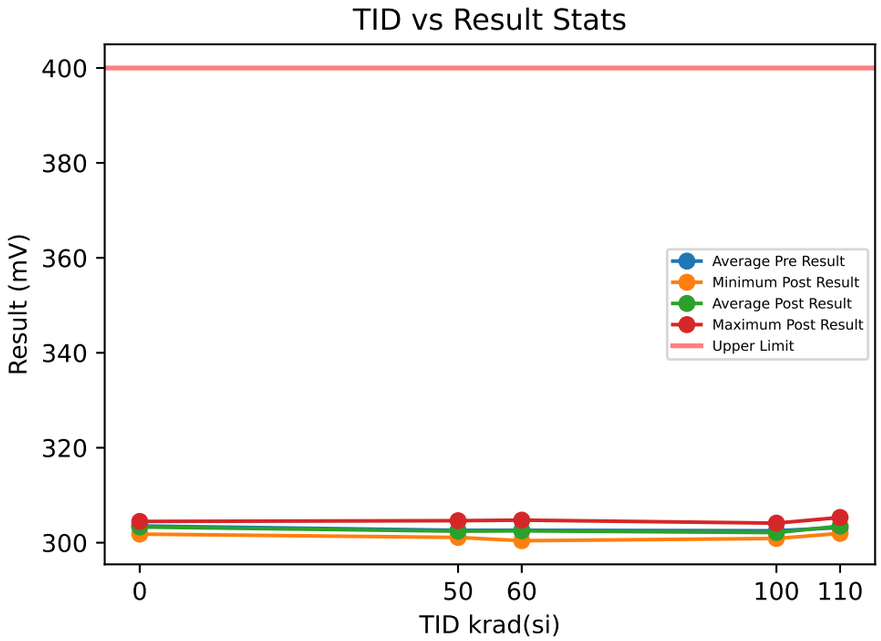
Test Results (No Limits Specified (%))

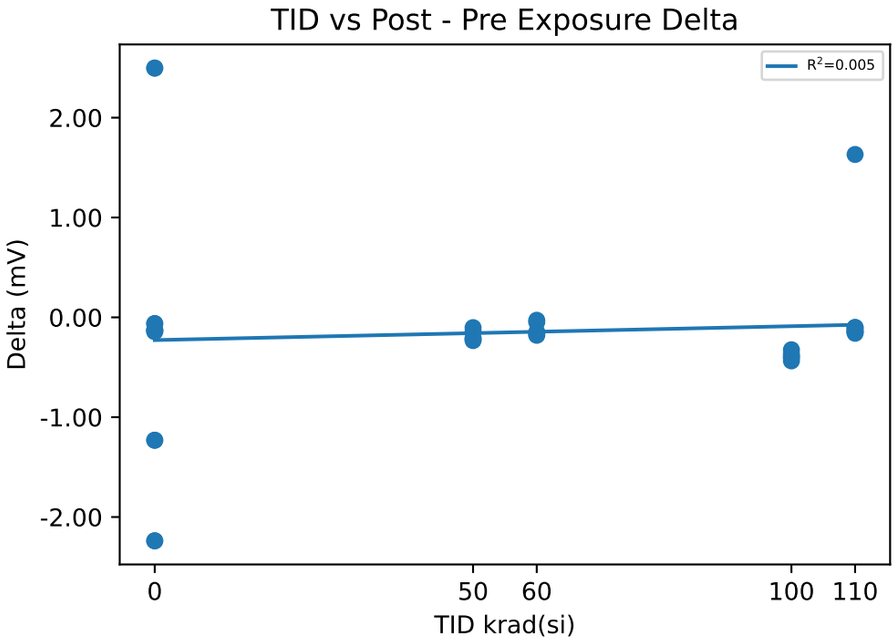
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.377e-13	9.375e-13	-0.0002
2	0	CU2	9.44e-13	9.438e-13	-0.0002
3	0	CU3	9.376e-13	9.372e-13	-0.0004
11	50	Unbiased-50k	9.402e-13	9.413e-13	0.0011
12	50	Unbiased-50k	9.374e-13	9.368e-13	-0.0006
13	50	Unbiased-50k	9.395e-13	9.388e-13	-0.0007
14	50	Unbiased-50k	9.39e-13	9.383e-13	-0.0007
16	50	Unbiased-50k	9.381e-13	9.386e-13	0.0005
17	60	Biased-50k	9.391e-13	9.389e-13	-0.0002
18	60	Biased-50k	9.38e-13	9.393e-13	0.0013
19	60	Biased-50k	9.386e-13	9.391e-13	0.0005
20	60	Biased-50k	9.385e-13	9.394e-13	0.0009
21	60	Biased-50k	9.416e-13	9.423e-13	0.0007
24	100	Unbiased-100k	9.379e-13	9.362e-13	-0.0017
25	100	Unbiased-100k	9.402e-13	9.398e-13	-0.0004
26	100	Unbiased-100k	9.395e-13	9.406e-13	0.0011
27	100	Unbiased-100k	9.39e-13	9.395e-13	0.0005
28	100	Unbiased-100k	9.411e-13	9.403e-13	-0.0008
29	110	Biased-100k	9.367e-13	9.383e-13	0.0016
30	110	Biased-100k	9.416e-13	9.42e-13	0.0004
31	110	Biased-100k	9.382e-13	9.401e-13	0.0019
32	110	Biased-100k	9.354e-13	9.369e-13	0.0015
34	110	Biased-100k	9.37e-13	9.394e-13	0.0024

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.376e-13	9.3977e-13	9.44e-13	3.6665e-15	9.372e-13	9.395e-13	9.438e-13	3.7269e-15	-0.0004	-0.00026667	-0.0002	0.00011547
50	9.374e-13	9.3884e-13	9.402e-13	1.1104e-15	9.368e-13	9.3876e-13	9.413e-13	1.6227e-15	-0.0007	-8e-05	0.0011	0.00083187
60	9.38e-13	9.3916e-13	9.416e-13	1.4188e-15	9.389e-13	9.398e-13	9.423e-13	1.4107e-15	-0.0002	0.00064	0.0013	0.00055498
100	9.379e-13	9.3954e-13	9.411e-13	1.2095e-15	9.362e-13	9.3928e-13	9.406e-13	1.774e-15	-0.0017	-0.00026	0.0011	0.0010968
110	9.354e-13	9.3778e-13	9.416e-13	2.3563e-15	9.369e-13	9.3934e-13	9.42e-13	1.9165e-15	0.0004	0.00156	0.0024	0.00073689

Device Test: 31.1 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD1/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





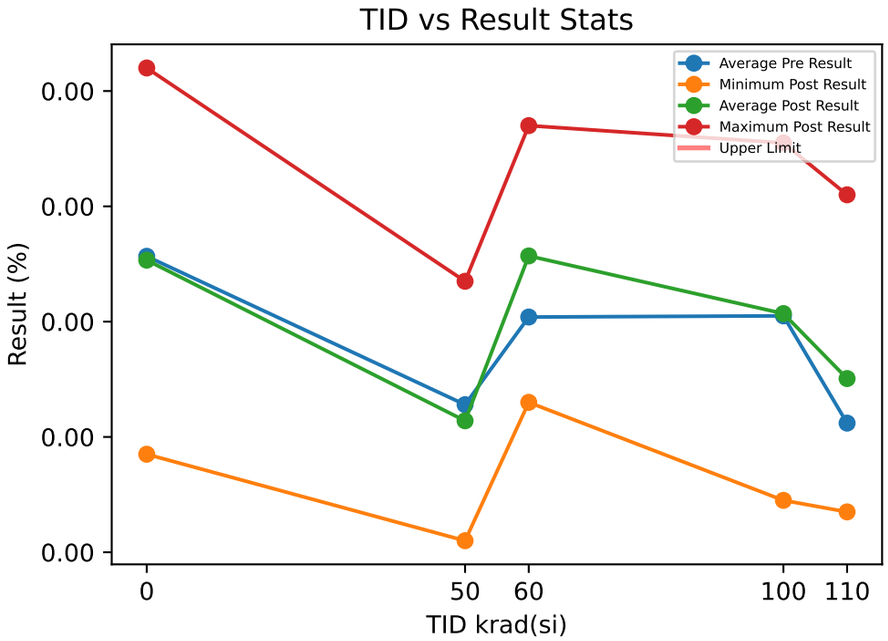
Test Results (Upper Limit = 400.0 (mV))

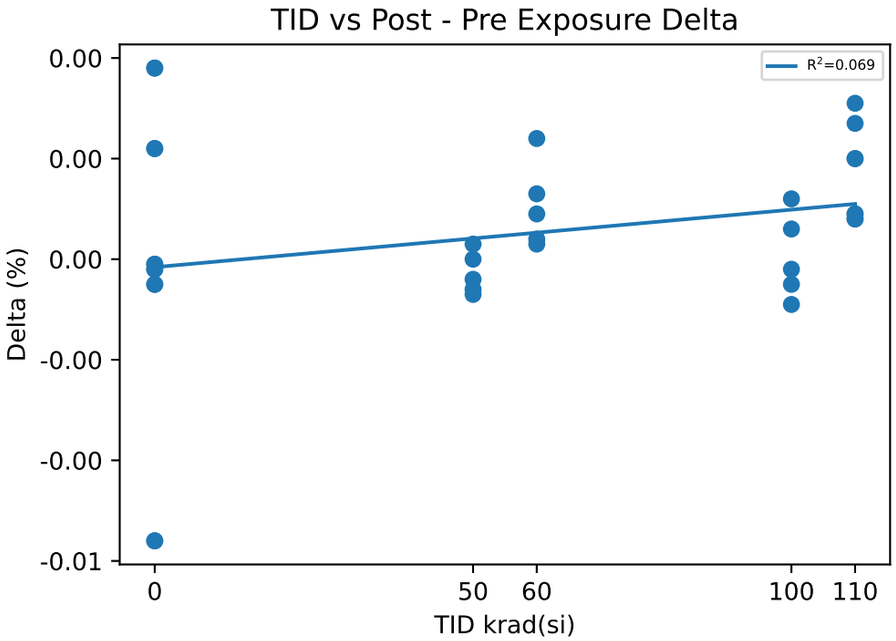
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	304.53	304.39	-0.1417
2	0	CU2	301.98	301.86	-0.1253
3	0	CU3	304.05	303.99	-0.0628
11	50	Unbiased-50k	302.32	302.1	-0.2196
12	50	Unbiased-50k	301.31	301.11	-0.2087
13	50	Unbiased-50k	301.74	301.64	-0.1031
14	50	Unbiased-50k	302.89	302.66	-0.2329
16	50	Unbiased-50k	304.78	304.64	-0.142
17	60	Biased-50k	304.06	303.89	-0.1722
18	60	Biased-50k	300.46	300.42	-0.0481
19	60	Biased-50k	302.33	302.3	-0.029
20	60	Biased-50k	301.29	301.15	-0.1462
21	60	Biased-50k	304.93	304.75	-0.1797
24	100	Unbiased-100k	303.08	302.68	-0.4034
25	100	Unbiased-100k	301.28	300.89	-0.3941
26	100	Unbiased-100k	302.13	301.69	-0.4362
27	100	Unbiased-100k	301.64	301.27	-0.3666
28	100	Unbiased-100k	304.44	304.12	-0.3247
29	110	Biased-100k	302.97	302.81	-0.1597
30	110	Biased-100k	305.46	305.32	-0.1454
31	110	Biased-100k	303.37	303.26	-0.1167
32	110	Biased-100k	300.33	301.96	1.6313
34	110	Biased-100k	303.76	303.62	-0.1424

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	301.98	303.52	304.53	1.3558	301.86	303.41	304.39	1.3624	-0.1417	-0.10993	-0.0628	0.041634
50	301.31	302.61	304.78	1.3503	301.11	302.43	304.64	1.3606	-0.2329	-0.18126	-0.1031	0.055991
60	300.46	302.62	304.93	1.866	300.42	302.5	304.75	1.8186	-0.1797	-0.11504	-0.029	0.071244
100	301.28	302.51	304.44	1.2732	300.89	302.13	304.12	1.2974	-0.4362	-0.385	-0.3247	0.041885
110	300.33	303.18	305.46	1.8538	301.96	303.39	305.32	1.2412	-0.1597	0.21342	1.6313	0.79277

Test: 31.10 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_RISING





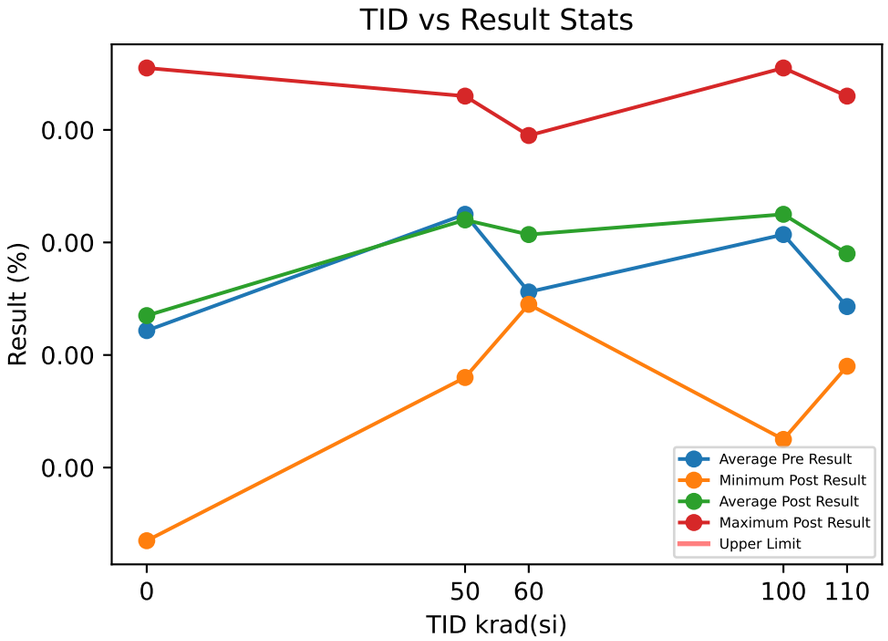
Test Results (No Limits Specified (%))

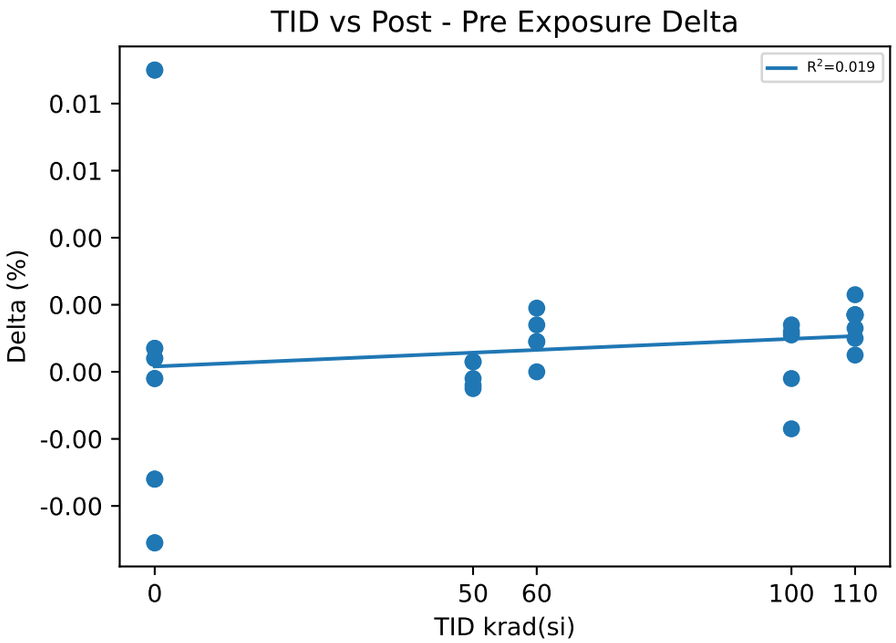
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.446e-13	9.444e-13	-0.0002
2	0	CU2	9.406e-13	9.405e-13	-0.0001
3	0	CU3	9.382e-13	9.377e-13	-0.0005
11	50	Unbiased-50k	9.407e-13	9.407e-13	0
12	50	Unbiased-50k	9.372e-13	9.375e-13	0.0003
13	50	Unbiased-50k	9.401e-13	9.395e-13	-0.0006
14	50	Unbiased-50k	9.382e-13	9.375e-13	-0.0007
16	50	Unbiased-50k	9.366e-13	9.362e-13	-0.0004
17	60	Biased-50k	9.377e-13	9.386e-13	0.0009
18	60	Biased-50k	9.417e-13	9.421e-13	0.0004
19	60	Biased-50k	9.376e-13	9.389e-13	0.0013
20	60	Biased-50k	9.431e-13	9.434e-13	0.0003
21	60	Biased-50k	9.403e-13	9.427e-13	0.0024
24	100	Unbiased-100k	9.392e-13	9.39e-13	-0.0002
25	100	Unbiased-100k	9.419e-13	9.431e-13	0.0012
26	100	Unbiased-100k	9.426e-13	9.421e-13	-0.0005
27	100	Unbiased-100k	9.39e-13	9.396e-13	0.0006
28	100	Unbiased-100k	9.378e-13	9.369e-13	-0.0009
29	110	Biased-100k	9.388e-13	9.419e-13	0.0031
30	110	Biased-100k	9.368e-13	9.388e-13	0.002
31	110	Biased-100k	9.402e-13	9.422e-13	0.002
32	110	Biased-100k	9.395e-13	9.422e-13	0.0027
34	110	Biased-100k	9.359e-13	9.367e-13	0.0008

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.382e-13	9.4113e-13	9.446e-13	3.2332e-15	9.377e-13	9.4087e-13	9.444e-13	3.365e-15	-0.0005	-0.00026667	-0.0001	0.00020817
50	9.366e-13	9.3856e-13	9.407e-13	1.7869e-15	9.362e-13	9.3828e-13	9.407e-13	1.795e-15	-0.0007	-0.00028	0.0003	0.00042071
60	9.376e-13	9.4008e-13	9.431e-13	2.4294e-15	9.386e-13	9.4114e-13	9.434e-13	2.2323e-15	0.0003	0.00106	0.0024	0.00085029
100	9.378e-13	9.401e-13	9.426e-13	2.0494e-15	9.369e-13	9.4014e-13	9.431e-13	2.4846e-15	-0.0009	4e-05	0.0012	0.00085029
110	9.359e-13	9.3824e-13	9.402e-13	1.8229e-15	9.367e-13	9.4036e-13	9.422e-13	2.4986e-15	0.0008	0.00212	0.0031	0.00087579

Test: 31.11 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_RISING





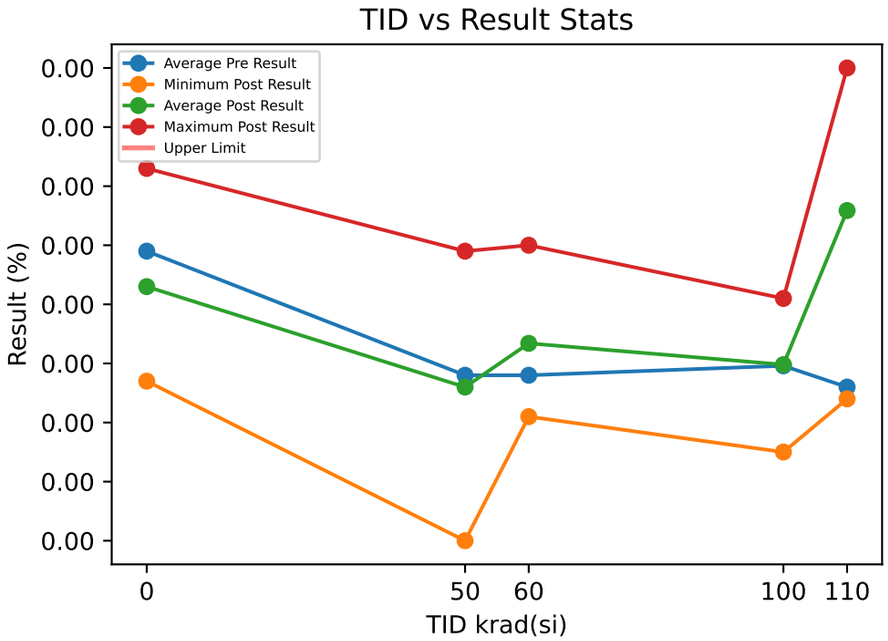
Test Results (No Limits Specified (%))

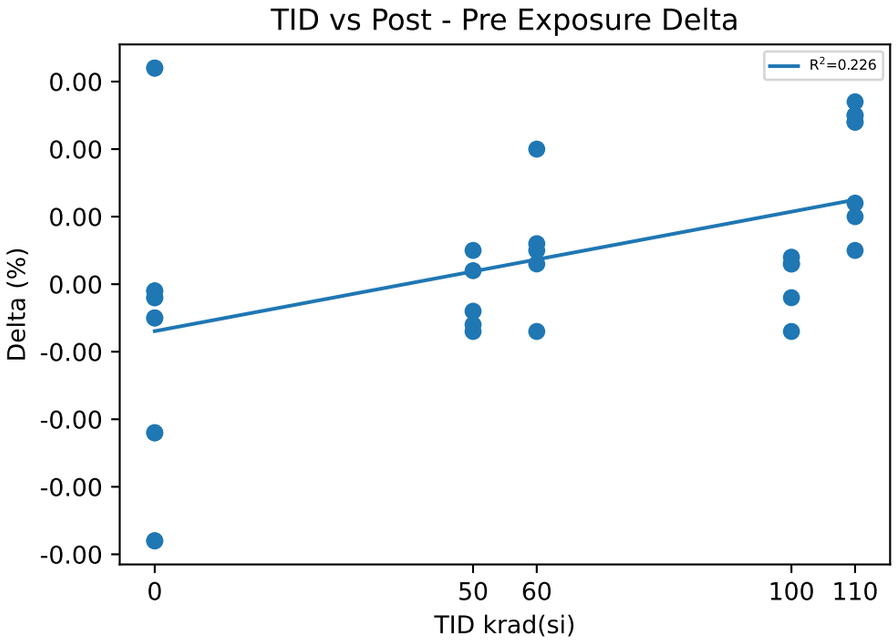
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.433e-13	9.431e-13	-0.0002
2	0	CU2	9.341e-13	9.348e-13	0.0007
3	0	CU3	9.379e-13	9.383e-13	0.0004
11	50	Unbiased-50k	9.373e-13	9.376e-13	0.0003
12	50	Unbiased-50k	9.42e-13	9.416e-13	-0.0004
13	50	Unbiased-50k	9.393e-13	9.388e-13	-0.0005
14	50	Unbiased-50k	9.411e-13	9.414e-13	0.0003
16	50	Unbiased-50k	9.428e-13	9.426e-13	-0.0002
17	60	Biased-50k	9.398e-13	9.407e-13	0.0009
18	60	Biased-50k	9.381e-13	9.4e-13	0.0019
19	60	Biased-50k	9.405e-13	9.419e-13	0.0014
20	60	Biased-50k	9.38e-13	9.389e-13	0.0009
21	60	Biased-50k	9.392e-13	9.392e-13	0
24	100	Unbiased-100k	9.367e-13	9.365e-13	-0.0002
25	100	Unbiased-100k	9.419e-13	9.431e-13	0.0012
26	100	Unbiased-100k	9.399e-13	9.41e-13	0.0011
27	100	Unbiased-100k	9.397e-13	9.411e-13	0.0014
28	100	Unbiased-100k	9.425e-13	9.408e-13	-0.0017
29	110	Biased-100k	9.384e-13	9.407e-13	0.0023
30	110	Biased-100k	9.421e-13	9.426e-13	0.0005
31	110	Biased-100k	9.368e-13	9.378e-13	0.001
32	110	Biased-100k	9.396e-13	9.409e-13	0.0013
34	110	Biased-100k	9.374e-13	9.391e-13	0.0017

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.341e-13	9.3843e-13	9.433e-13	4.6231e-15	9.348e-13	9.3873e-13	9.431e-13	4.1669e-15	-0.0002	0.0003	0.0007	0.00045826
50	9.373e-13	9.405e-13	9.428e-13	2.2125e-15	9.376e-13	9.404e-13	9.426e-13	2.1024e-15	-0.0005	-0.0001	0.0003	0.00038079
60	9.38e-13	9.3912e-13	9.405e-13	1.0803e-15	9.389e-13	9.4014e-13	9.419e-13	1.2095e-15	0	0.00102	0.0019	0.00070498
100	9.367e-13	9.4014e-13	9.425e-13	2.2777e-15	9.365e-13	9.405e-13	9.431e-13	2.4218e-15	-0.0017	0.00036	0.0014	0.0013126
110	9.368e-13	9.3886e-13	9.421e-13	2.0995e-15	9.378e-13	9.4022e-13	9.426e-13	1.8349e-15	0.0005	0.00136	0.0023	0.00068411

Test: 31.12 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_RISING





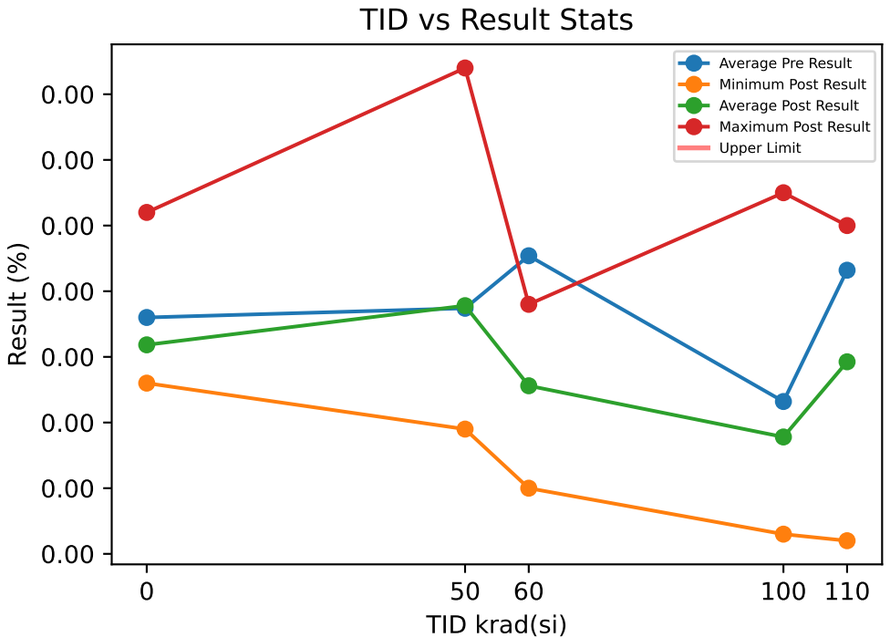
Test Results (No Limits Specified (%))

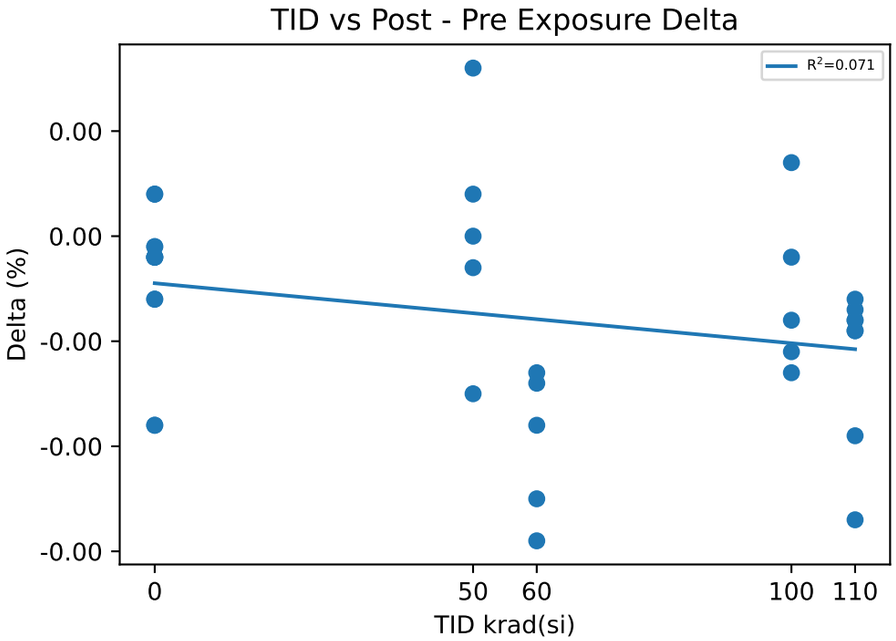
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.435e-13	9.433e-13	-0.0002
2	0	CU2	9.401e-13	9.4e-13	-0.0001
3	0	CU3	9.421e-13	9.416e-13	-0.0005
11	50	Unbiased-50k	9.376e-13	9.378e-13	0.0002
12	50	Unbiased-50k	9.412e-13	9.408e-13	-0.0004
13	50	Unbiased-50k	9.411e-13	9.405e-13	-0.0006
14	50	Unbiased-50k	9.377e-13	9.37e-13	-0.0007
16	50	Unbiased-50k	9.414e-13	9.419e-13	0.0005
17	60	Biased-50k	9.406e-13	9.399e-13	-0.0007
18	60	Biased-50k	9.408e-13	9.411e-13	0.0003
19	60	Biased-50k	9.386e-13	9.391e-13	0.0005
20	60	Biased-50k	9.4e-13	9.42e-13	0.002
21	60	Biased-50k	9.39e-13	9.396e-13	0.0006
24	100	Unbiased-100k	9.387e-13	9.385e-13	-0.0002
25	100	Unbiased-100k	9.39e-13	9.393e-13	0.0003
26	100	Unbiased-100k	9.401e-13	9.404e-13	0.0003
27	100	Unbiased-100k	9.407e-13	9.411e-13	0.0004
28	100	Unbiased-100k	9.413e-13	9.406e-13	-0.0007
29	110	Biased-100k	9.389e-13	9.394e-13	0.0005
30	110	Biased-100k	9.386e-13	9.398e-13	0.0012
31	110	Biased-100k	9.384e-13	9.394e-13	0.001
32	110	Biased-100k	9.396e-13	9.423e-13	0.0027
34	110	Biased-100k	9.425e-13	9.449e-13	0.0024

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.401e-13	9.419e-13	9.435e-13	1.7088e-15	9.4e-13	9.4163e-13	9.433e-13	1.6503e-15	-0.0005	-0.00026667	-0.0001	0.00020817
50	9.376e-13	9.398e-13	9.414e-13	1.966e-15	9.37e-13	9.396e-13	9.419e-13	2.094e-15	-0.0007	-0.0002	0.0005	0.0005244
60	9.386e-13	9.398e-13	9.408e-13	9.6954e-16	9.391e-13	9.4034e-13	9.42e-13	1.1845e-15	-0.0007	0.00054	0.002	0.00096592
100	9.387e-13	9.3996e-13	9.413e-13	1.1036e-15	9.385e-13	9.3998e-13	9.411e-13	1.0569e-15	-0.0007	2e-05	0.0004	0.00046583
110	9.384e-13	9.396e-13	9.425e-13	1.6837e-15	9.394e-13	9.4116e-13	9.449e-13	2.4152e-15	0.0005	0.00156	0.0027	0.00094499

Test: 31.13 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_RISING





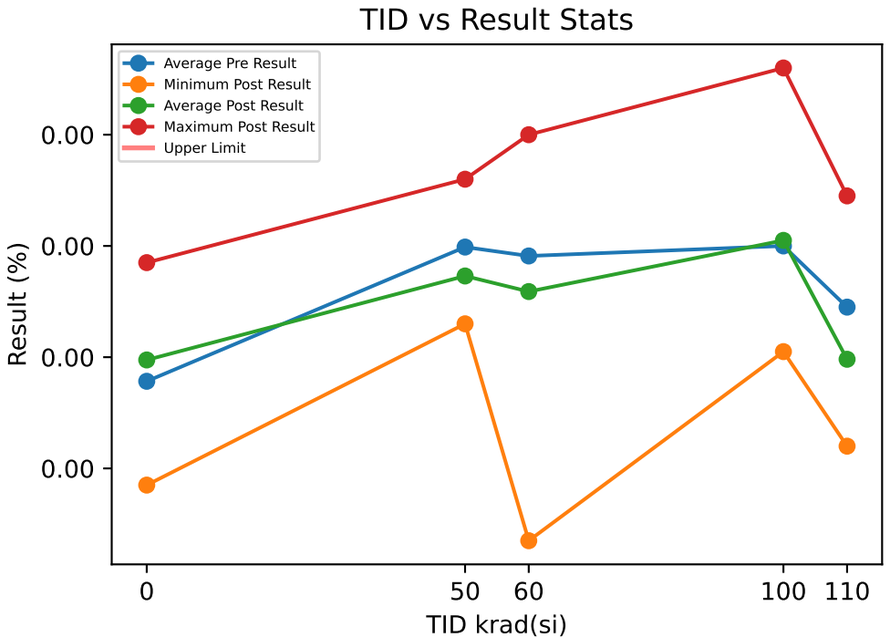
Test Results (No Limits Specified (%))

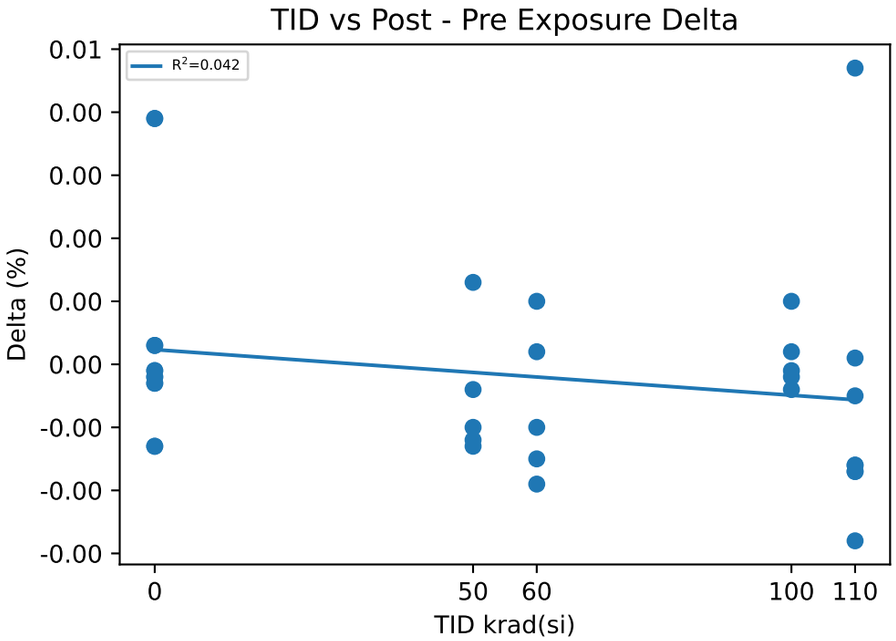
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0908e-12	1.0906e-12	-0.0002
2	0	CU2	1.0912e-12	1.091e-12	-0.0002
3	0	CU3	1.0928e-12	1.0932e-12	0.0004
11	50	Unbiased-50k	1.0905e-12	1.0902e-12	-0.0003
12	50	Unbiased-50k	1.0896e-12	1.0912e-12	0.0016
13	50	Unbiased-50k	1.0937e-12	1.0922e-12	-0.0015
14	50	Unbiased-50k	1.095e-12	1.0954e-12	0.0004
16	50	Unbiased-50k	1.0899e-12	1.0899e-12	0
17	60	Biased-50k	1.0931e-12	1.0918e-12	-0.0013
18	60	Biased-50k	1.0928e-12	1.0914e-12	-0.0014
19	60	Biased-50k	1.0919e-12	1.089e-12	-0.0029
20	60	Biased-50k	1.0926e-12	1.0901e-12	-0.0025
21	60	Biased-50k	1.0923e-12	1.0905e-12	-0.0018
24	100	Unbiased-100k	1.0896e-12	1.0883e-12	-0.0013
25	100	Unbiased-100k	1.0901e-12	1.089e-12	-0.0011
26	100	Unbiased-100k	1.0891e-12	1.0898e-12	0.0007
27	100	Unbiased-100k	1.0885e-12	1.0883e-12	-0.0002
28	100	Unbiased-100k	1.0943e-12	1.0935e-12	-0.0008
29	110	Biased-100k	1.0952e-12	1.0925e-12	-0.0027
30	110	Biased-100k	1.0888e-12	1.0882e-12	-0.0006
31	110	Biased-100k	1.0937e-12	1.093e-12	-0.0007
32	110	Biased-100k	1.0922e-12	1.0903e-12	-0.0019
34	110	Biased-100k	1.0917e-12	1.0908e-12	-0.0009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0908e-12	1.0916e-12	1.0928e-12	1.0583e-15	1.0906e-12	1.0916e-12	1.0932e-12	1.4e-15	-0.0002	0	0.0004	0.00034641
50	1.0896e-12	1.0917e-12	1.095e-12	2.4481e-15	1.0899e-12	1.0918e-12	1.0954e-12	2.2163e-15	-0.0015	4e-05	0.0016	0.0011238
60	1.0919e-12	1.0925e-12	1.0931e-12	4.6152e-16	1.089e-12	1.0906e-12	1.0918e-12	1.1059e-15	-0.0029	-0.00198	-0.0013	0.00069785
100	1.0885e-12	1.0903e-12	1.0943e-12	2.3026e-15	1.0883e-12	1.0898e-12	1.0935e-12	2.1696e-15	-0.0013	-0.00054	0.0007	0.00080808
110	1.0888e-12	1.0923e-12	1.0952e-12	2.3973e-15	1.0882e-12	1.091e-12	1.093e-12	1.9113e-15	-0.0027	-0.00136	-0.0006	0.00090995

Test: 31.14 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_RISING





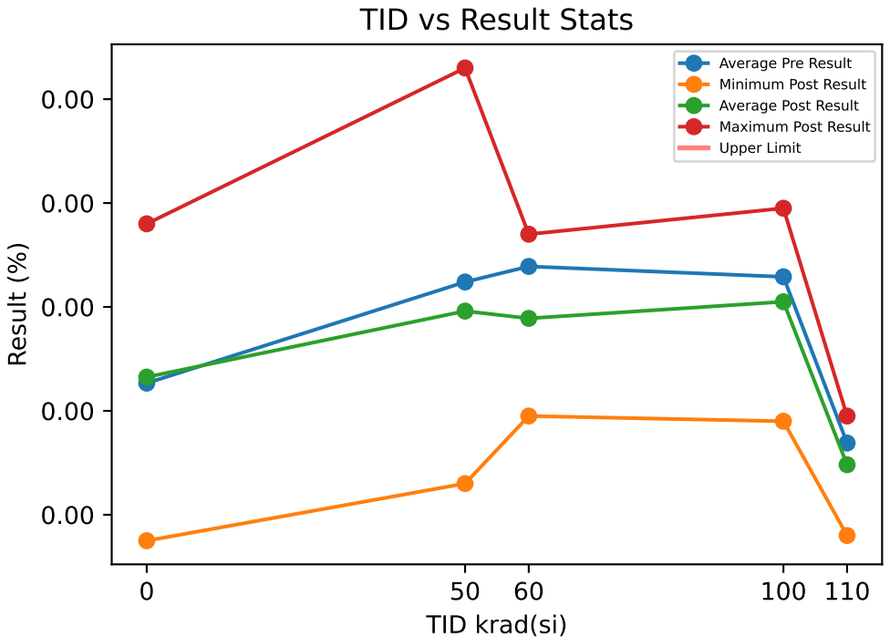
Test Results (No Limits Specified (%))

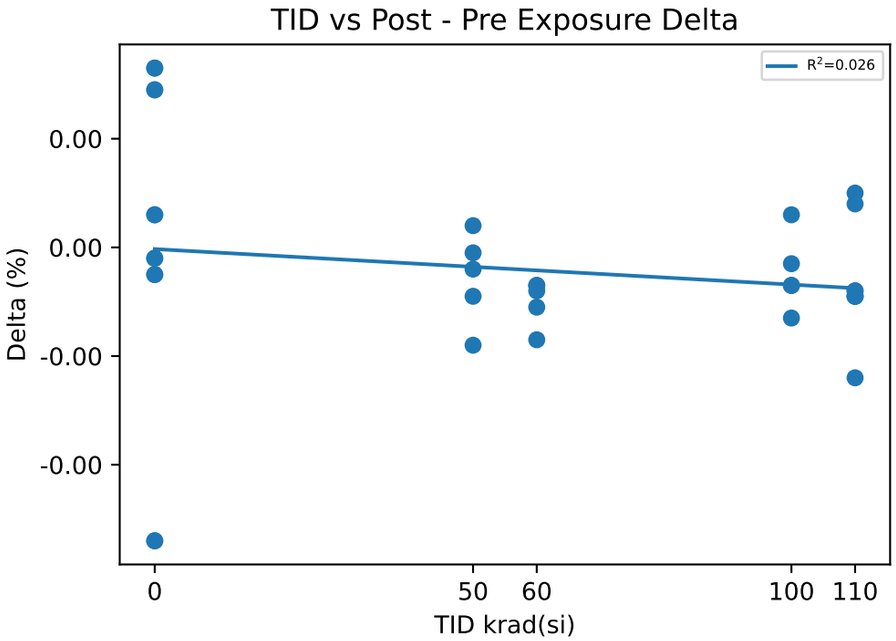
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0919e-12	1.0917e-12	-0.0002
2	0	CU2	1.0878e-12	1.0877e-12	-0.0001
3	0	CU3	1.089e-12	1.0893e-12	0.0003
11	50	Unbiased-50k	1.0908e-12	1.0921e-12	0.0013
12	50	Unbiased-50k	1.0944e-12	1.0932e-12	-0.0012
13	50	Unbiased-50k	1.092e-12	1.0907e-12	-0.0013
14	50	Unbiased-50k	1.091e-12	1.0906e-12	-0.0004
16	50	Unbiased-50k	1.0917e-12	1.0907e-12	-0.001
17	60	Biased-50k	1.0886e-12	1.0867e-12	-0.0019
18	60	Biased-50k	1.0939e-12	1.0924e-12	-0.0015
19	60	Biased-50k	1.092e-12	1.0922e-12	0.0002
20	60	Biased-50k	1.095e-12	1.094e-12	-0.001
21	60	Biased-50k	1.0896e-12	1.0906e-12	0.001
24	100	Unbiased-100k	1.0905e-12	1.0915e-12	0.001
25	100	Unbiased-100k	1.0904e-12	1.0902e-12	-0.0002
26	100	Unbiased-100k	1.0939e-12	1.0935e-12	-0.0004
27	100	Unbiased-100k	1.0953e-12	1.0952e-12	-0.0001
28	100	Unbiased-100k	1.0899e-12	1.0901e-12	0.0002
29	110	Biased-100k	1.0954e-12	1.0926e-12	-0.0028
30	110	Biased-100k	1.0887e-12	1.0888e-12	0.0001
31	110	Biased-100k	1.0921e-12	1.0916e-12	-0.0005
32	110	Biased-100k	1.0882e-12	1.0929e-12	0.0047
34	110	Biased-100k	1.0901e-12	1.0884e-12	-0.0017

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0878e-12	1.0896e-12	1.0919e-12	2.1079e-15	1.0877e-12	1.0896e-12	1.0917e-12	2.0133e-15	-0.0002	-1.4803e-16	0.0003	0.00026458
50	1.0908e-12	1.092e-12	1.0944e-12	1.4394e-15	1.0906e-12	1.0915e-12	1.0932e-12	1.1546e-15	-0.0013	-0.00052	0.0013	0.0010756
60	1.0886e-12	1.0918e-12	1.095e-12	2.728e-15	1.0867e-12	1.0912e-12	1.094e-12	2.7788e-15	-0.0019	-0.00064	0.001	0.0012095
100	1.0899e-12	1.092e-12	1.0953e-12	2.4352e-15	1.0901e-12	1.0921e-12	1.0952e-12	2.2102e-15	-0.0004	0.0001	0.001	0.00054772
110	1.0882e-12	1.0909e-12	1.0954e-12	2.9351e-15	1.0884e-12	1.0909e-12	1.0929e-12	2.1232e-15	-0.0028	-4e-05	0.0047	0.0028754

Test: 31.15 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_RISING





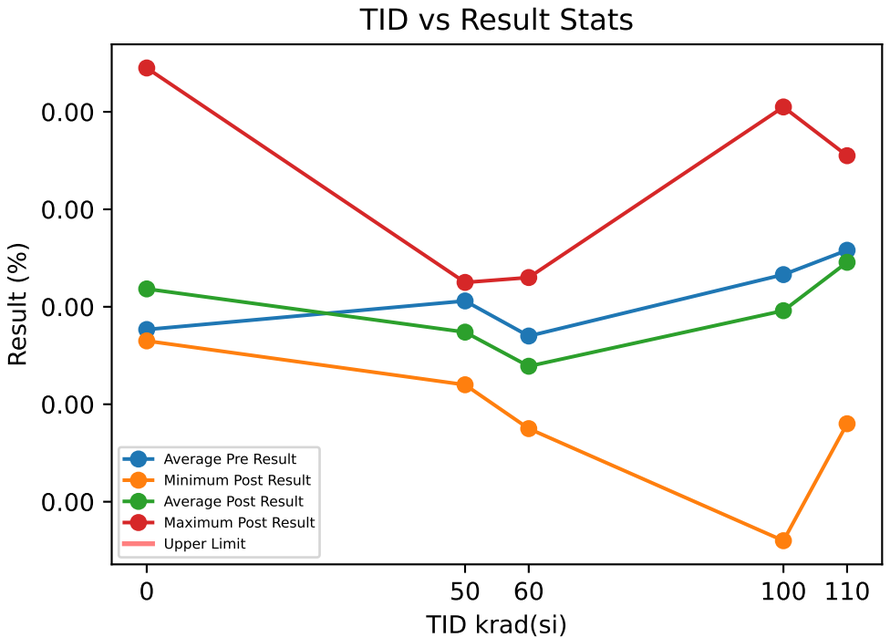
Test Results (No Limits Specified (%))

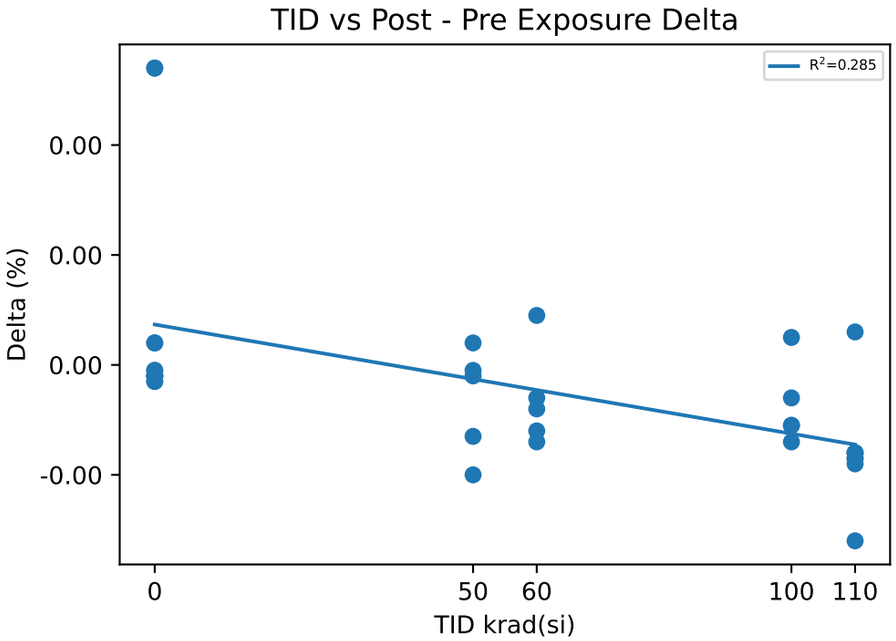
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0929e-12	1.0927e-12	-0.0002
2	0	CU2	1.0907e-12	1.0913e-12	0.0006
3	0	CU3	1.088e-12	1.0875e-12	-0.0005
11	50	Unbiased-50k	1.0923e-12	1.0905e-12	-0.0018
12	50	Unbiased-50k	1.0967e-12	1.0966e-12	-0.0001
13	50	Unbiased-50k	1.0911e-12	1.0915e-12	0.0004
14	50	Unbiased-50k	1.089e-12	1.0886e-12	-0.0004
16	50	Unbiased-50k	1.0933e-12	1.0924e-12	-0.0009
17	60	Biased-50k	1.0927e-12	1.0916e-12	-0.0011
18	60	Biased-50k	1.0944e-12	1.0927e-12	-0.0017
19	60	Biased-50k	1.0941e-12	1.0934e-12	-0.0007
20	60	Biased-50k	1.0907e-12	1.0899e-12	-0.0008
21	60	Biased-50k	1.092e-12	1.0913e-12	-0.0007
24	100	Unbiased-100k	1.0905e-12	1.0898e-12	-0.0007
25	100	Unbiased-100k	1.0942e-12	1.0939e-12	-0.0003
26	100	Unbiased-100k	1.0944e-12	1.0931e-12	-0.0013
27	100	Unbiased-100k	1.0924e-12	1.093e-12	0.0006
28	100	Unbiased-100k	1.0914e-12	1.0907e-12	-0.0007
29	110	Biased-100k	1.0905e-12	1.0896e-12	-0.0009
30	110	Biased-100k	1.0874e-12	1.0884e-12	0.001
31	110	Biased-100k	1.09e-12	1.0876e-12	-0.0024
32	110	Biased-100k	1.0891e-12	1.0899e-12	0.0008
34	110	Biased-100k	1.0899e-12	1.089e-12	-0.0009

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.088e-12	1.0905e-12	1.0929e-12	2.4542e-15	1.0875e-12	1.0905e-12	1.0927e-12	2.6907e-15	-0.0005	-3.3333e-05	0.0006	0.00056862
50	1.089e-12	1.0925e-12	1.0967e-12	2.8517e-15	1.0886e-12	1.0919e-12	1.0966e-12	2.9727e-15	-0.0018	-0.00056	0.0004	0.00083845
60	1.0907e-12	1.0928e-12	1.0944e-12	1.5255e-15	1.0899e-12	1.0918e-12	1.0934e-12	1.348e-15	-0.0017	-0.001	-0.0007	0.00042426
100	1.0905e-12	1.0926e-12	1.0944e-12	1.7094e-15	1.0898e-12	1.0921e-12	1.0939e-12	1.7536e-15	-0.0013	-0.00048	0.0006	0.00070143
110	1.0874e-12	1.0894e-12	1.0905e-12	1.2153e-15	1.0876e-12	1.0889e-12	1.0899e-12	9.2736e-16	-0.0024	-0.00048	0.001	0.0014025

Test: 31.16 VSENSE_VTH_RISING_FAULT(PWRGD|RisingFault/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_RISING





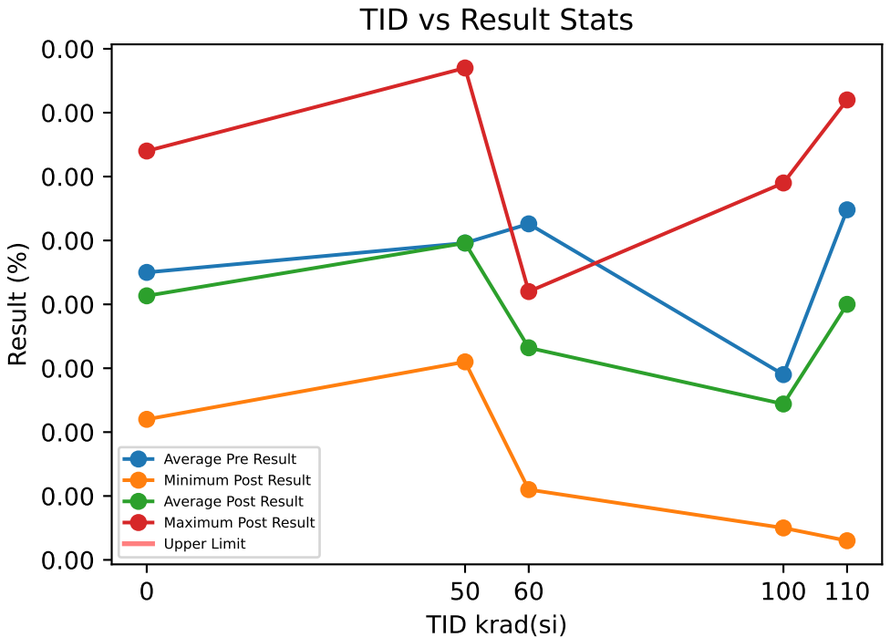
Test Results (No Limits Specified (%))

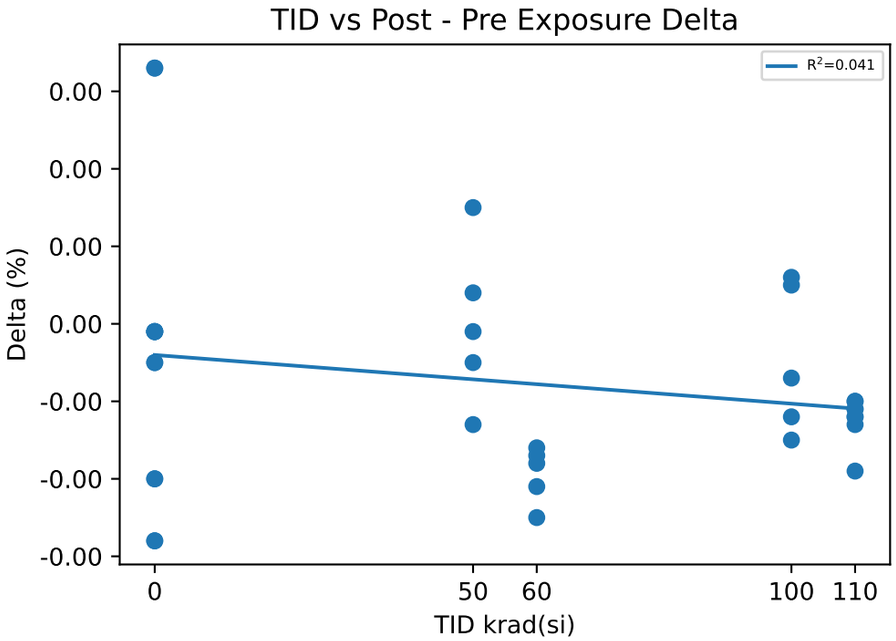
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0915e-12	1.0913e-12	-0.0002
2	0	CU2	1.0915e-12	1.0914e-12	-0.0001
3	0	CU3	1.0916e-12	1.092e-12	0.0004
11	50	Unbiased-50k	1.0935e-12	1.0915e-12	-0.002
12	50	Unbiased-50k	1.0914e-12	1.0913e-12	-0.0001
13	50	Unbiased-50k	1.093e-12	1.0917e-12	-0.0013
14	50	Unbiased-50k	1.09e-12	1.0904e-12	0.0004
16	50	Unbiased-50k	1.0927e-12	1.0925e-12	-0.0002
17	60	Biased-50k	1.0917e-12	1.0905e-12	-0.0012
18	60	Biased-50k	1.0911e-12	1.0905e-12	-0.0006
19	60	Biased-50k	1.0922e-12	1.0908e-12	-0.0014
20	60	Biased-50k	1.0903e-12	1.0895e-12	-0.0008
21	60	Biased-50k	1.0917e-12	1.0926e-12	0.0009
24	100	Unbiased-100k	1.0926e-12	1.0912e-12	-0.0014
25	100	Unbiased-100k	1.0883e-12	1.0872e-12	-0.0011
26	100	Unbiased-100k	1.0956e-12	1.0961e-12	0.0005
27	100	Unbiased-100k	1.0957e-12	1.0946e-12	-0.0011
28	100	Unbiased-100k	1.0911e-12	1.0905e-12	-0.0006
29	110	Biased-100k	1.0918e-12	1.09e-12	-0.0018
30	110	Biased-100k	1.0923e-12	1.0907e-12	-0.0016
31	110	Biased-100k	1.0928e-12	1.0896e-12	-0.0032
32	110	Biased-100k	1.0922e-12	1.0928e-12	0.0006
34	110	Biased-100k	1.0967e-12	1.095e-12	-0.0017

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0915e-12	1.0915e-12	1.0916e-12	5.7735e-17	1.0913e-12	1.0916e-12	1.092e-12	3.7859e-16	-0.0002	3.3333e-05	0.0004	0.00032146
50	1.09e-12	1.0921e-12	1.0935e-12	1.4167e-15	1.0904e-12	1.0915e-12	1.0925e-12	7.5631e-16	-0.002	-0.00064	0.0004	0.00098133
60	1.0903e-12	1.0914e-12	1.0922e-12	7.2801e-16	1.0895e-12	1.0908e-12	1.0926e-12	1.13e-15	-0.0014	-0.00062	0.0009	0.00090664
100	1.0883e-12	1.0927e-12	1.0957e-12	3.1358e-15	1.0872e-12	1.0919e-12	1.0961e-12	3.5167e-15	-0.0014	-0.00074	0.0005	0.00075033
110	1.0918e-12	1.0932e-12	1.0967e-12	2.0107e-15	1.0896e-12	1.0916e-12	1.095e-12	2.2565e-15	-0.0032	-0.00154	0.0006	0.0013631

st: 31.17 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_FALLIN





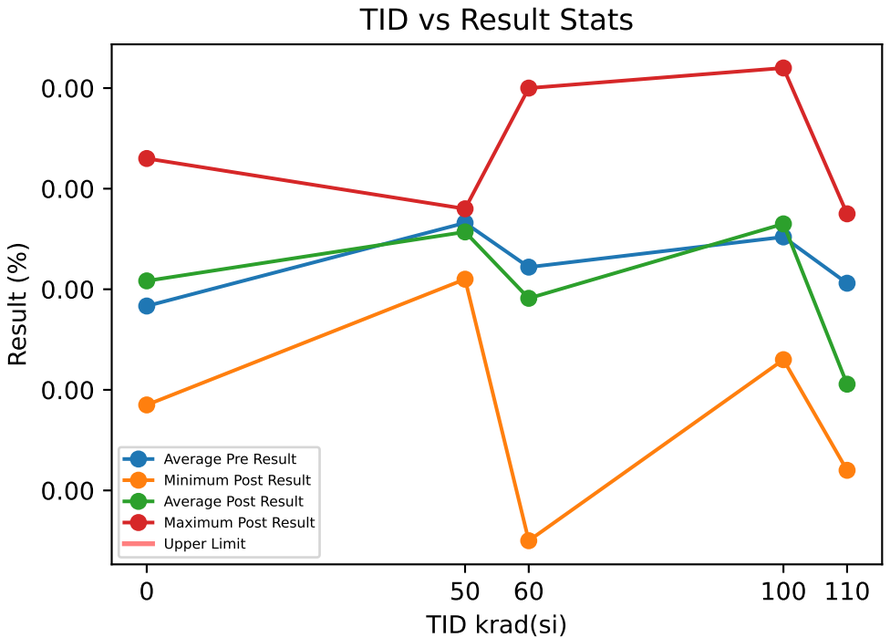
Test Results (No Limits Specified (%))

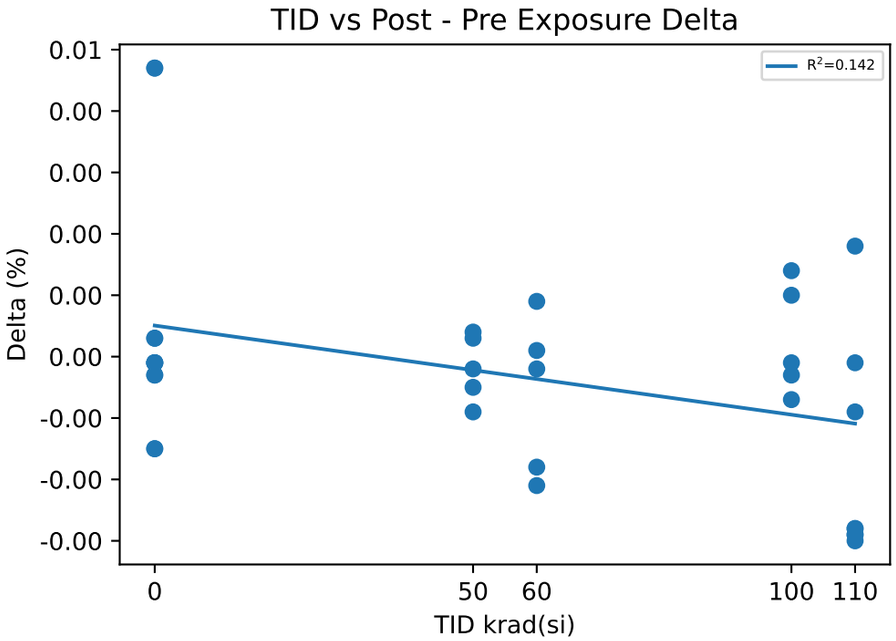
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0584e-12	1.0583e-12	-0.0001
2	0	CU2	1.0602e-12	1.0601e-12	-0.0001
3	0	CU3	1.0629e-12	1.0624e-12	-0.0005
11	50	Unbiased-50k	1.0605e-12	1.06e-12	-0.0005
12	50	Unbiased-50k	1.059e-12	1.0605e-12	0.0015
13	50	Unbiased-50k	1.0628e-12	1.0615e-12	-0.0013
14	50	Unbiased-50k	1.0633e-12	1.0637e-12	0.0004
16	50	Unbiased-50k	1.0592e-12	1.0591e-12	-0.0001
17	60	Biased-50k	1.0623e-12	1.0602e-12	-0.0021
18	60	Biased-50k	1.0612e-12	1.0594e-12	-0.0018
19	60	Biased-50k	1.0596e-12	1.0571e-12	-0.0025
20	60	Biased-50k	1.0618e-12	1.0601e-12	-0.0017
21	60	Biased-50k	1.0614e-12	1.0598e-12	-0.0016
24	100	Unbiased-100k	1.0589e-12	1.0574e-12	-0.0015
25	100	Unbiased-100k	1.0577e-12	1.0565e-12	-0.0012
26	100	Unbiased-100k	1.0576e-12	1.0582e-12	0.0006
27	100	Unbiased-100k	1.0577e-12	1.0582e-12	0.0005
28	100	Unbiased-100k	1.0626e-12	1.0619e-12	-0.0007
29	110	Biased-100k	1.0651e-12	1.0632e-12	-0.0019
30	110	Biased-100k	1.0573e-12	1.0563e-12	-0.001
31	110	Biased-100k	1.0628e-12	1.0618e-12	-0.001
32	110	Biased-100k	1.0614e-12	1.0601e-12	-0.0013
34	110	Biased-100k	1.0608e-12	1.0596e-12	-0.0012

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0584e-12	1.0605e-12	1.0629e-12	2.265e-15	1.0583e-12	1.0603e-12	1.0624e-12	2.0551e-15	-0.0005	-0.00023333	-0.0001	0.00023094
50	1.059e-12	1.061e-12	1.0633e-12	2.0007e-15	1.0591e-12	1.061e-12	1.0637e-12	1.7601e-15	-0.0013	8.8818e-17	0.0015	0.001044
60	1.0596e-12	1.0613e-12	1.0623e-12	1.0188e-15	1.0571e-12	1.0593e-12	1.0602e-12	1.2795e-15	-0.0025	-0.00194	-0.0016	0.00036469
100	1.0576e-12	1.0589e-12	1.0626e-12	2.1366e-15	1.0565e-12	1.0584e-12	1.0619e-12	2.0574e-15	-0.0015	-0.00046	0.0006	0.00096592
110	1.0573e-12	1.0615e-12	1.0651e-12	2.863e-15	1.0563e-12	1.0602e-12	1.0632e-12	2.6048e-15	-0.0019	-0.00128	-0.001	0.00037014

st: 31.18 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_FALLIN





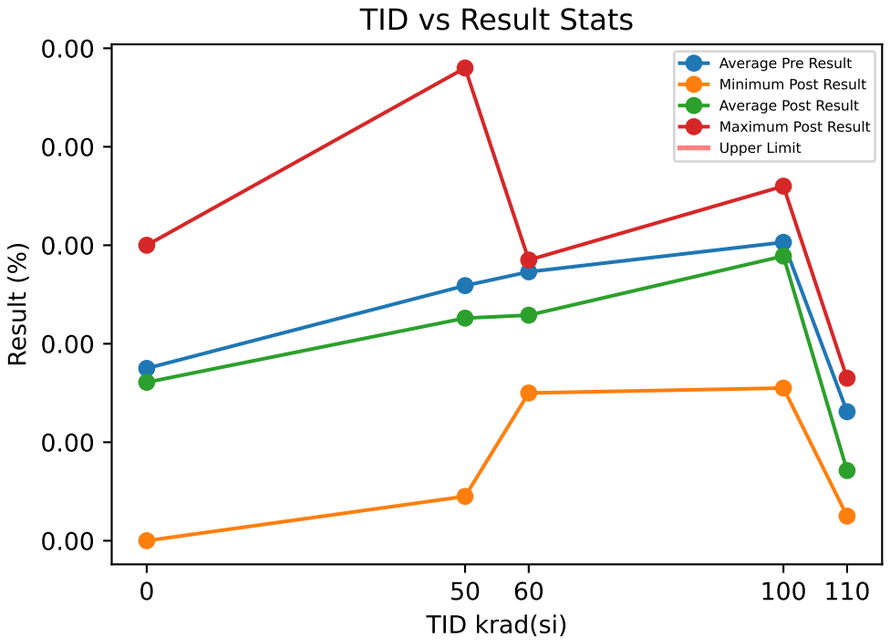
Test Results (No Limits Specified (%))

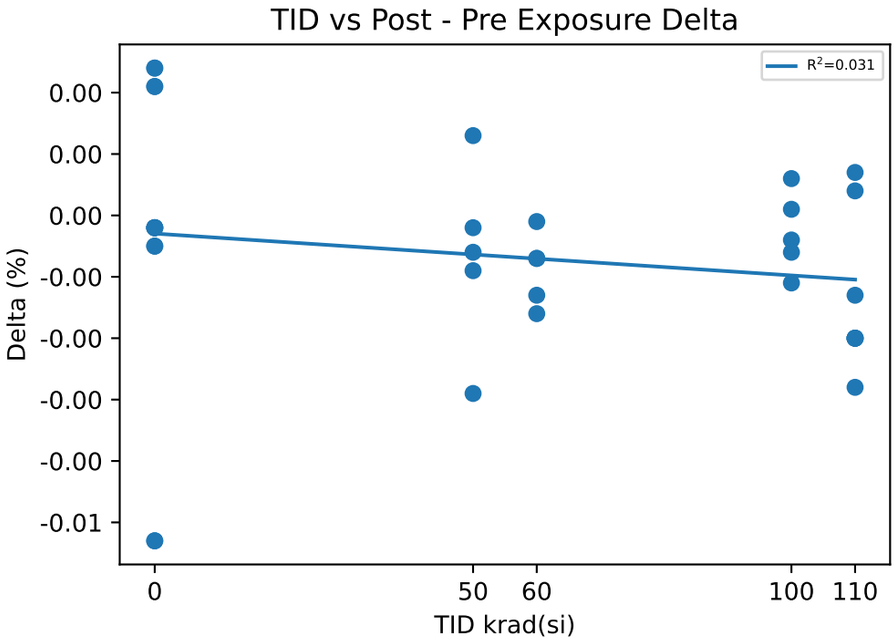
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0619e-12	1.0618e-12	-0.0001
2	0	CU2	1.0579e-12	1.0578e-12	-0.0001
3	0	CU3	1.0592e-12	1.0595e-12	0.0003
11	50	Unbiased-50k	1.0599e-12	1.0602e-12	0.0003
12	50	Unbiased-50k	1.0618e-12	1.0616e-12	-0.0002
13	50	Unbiased-50k	1.0621e-12	1.0616e-12	-0.0005
14	50	Unbiased-50k	1.0611e-12	1.0615e-12	0.0004
16	50	Unbiased-50k	1.0617e-12	1.0608e-12	-0.0009
17	60	Biased-50k	1.0571e-12	1.055e-12	-0.0021
18	60	Biased-50k	1.0615e-12	1.0597e-12	-0.0018
19	60	Biased-50k	1.0613e-12	1.0614e-12	0.0001
20	60	Biased-50k	1.0642e-12	1.064e-12	-0.0002
21	60	Biased-50k	1.0581e-12	1.059e-12	0.0009
24	100	Unbiased-100k	1.0589e-12	1.0599e-12	0.001
25	100	Unbiased-100k	1.0589e-12	1.0586e-12	-0.0003
26	100	Unbiased-100k	1.063e-12	1.0644e-12	0.0014
27	100	Unbiased-100k	1.0644e-12	1.0643e-12	-0.0001
28	100	Unbiased-100k	1.06e-12	1.0593e-12	-0.0007
29	110	Biased-100k	1.0645e-12	1.0615e-12	-0.003
30	110	Biased-100k	1.0572e-12	1.0571e-12	-0.0001
31	110	Biased-100k	1.0613e-12	1.0604e-12	-0.0009
32	110	Biased-100k	1.0583e-12	1.0601e-12	0.0018
34	110	Biased-100k	1.0593e-12	1.0564e-12	-0.0029

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0579e-12	1.0597e-12	1.0619e-12	2.0404e-15	1.0578e-12	1.0597e-12	1.0618e-12	2.0075e-15	-0.0001	3.3333e-05	0.0003	0.00023094
50	1.0599e-12	1.0613e-12	1.0621e-12	8.7293e-16	1.0602e-12	1.0611e-12	1.0616e-12	6.229e-16	-0.0009	-0.00018	0.0004	0.00054498
60	1.0571e-12	1.0604e-12	1.0642e-12	2.8562e-15	1.055e-12	1.0598e-12	1.064e-12	3.3124e-15	-0.0021	-0.00062	0.0009	0.0012834
100	1.0589e-12	1.061e-12	1.0644e-12	2.5185e-15	1.0586e-12	1.0613e-12	1.0644e-12	2.8222e-15	-0.0007	0.00026	0.0014	0.0008961
110	1.0572e-12	1.0601e-12	1.0645e-12	2.8761e-15	1.0564e-12	1.0591e-12	1.0615e-12	2.2215e-15	-0.003	-0.00102	0.0018	0.0020167

st: 31.19 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_FALLIN





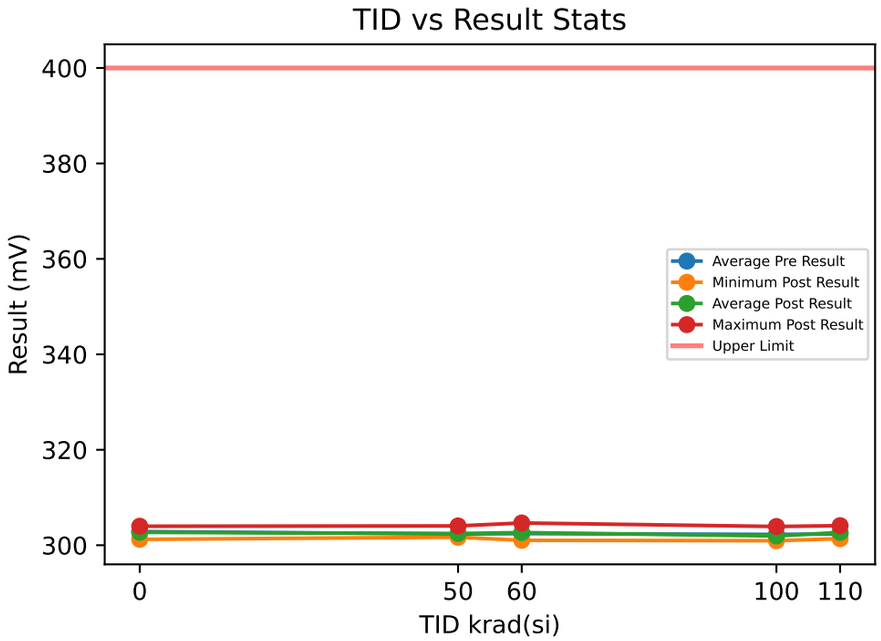
Test Results (No Limits Specified (%))

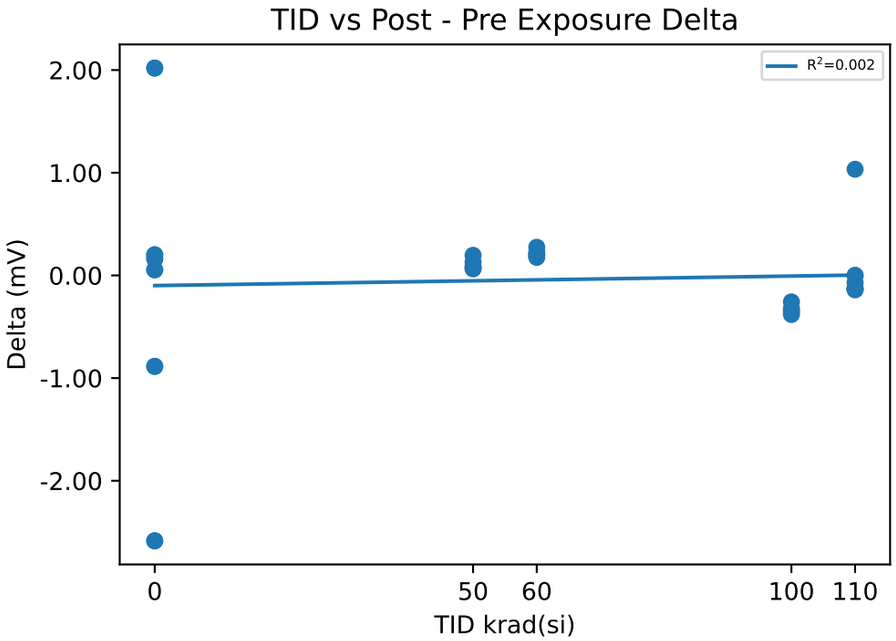
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0613e-12	1.0611e-12	-0.0002
2	0	CU2	1.0599e-12	1.0597e-12	-0.0002
3	0	CU3	1.0573e-12	1.0568e-12	-0.0005
11	50	Unbiased-50k	1.0607e-12	1.0578e-12	-0.0029
12	50	Unbiased-50k	1.0658e-12	1.0656e-12	-0.0002
13	50	Unbiased-50k	1.0586e-12	1.0599e-12	0.0013
14	50	Unbiased-50k	1.0575e-12	1.0569e-12	-0.0006
16	50	Unbiased-50k	1.0633e-12	1.0624e-12	-0.0009
17	60	Biased-50k	1.0603e-12	1.059e-12	-0.0013
18	60	Biased-50k	1.0626e-12	1.061e-12	-0.0016
19	60	Biased-50k	1.0624e-12	1.0617e-12	-0.0007
20	60	Biased-50k	1.06e-12	1.0599e-12	-0.0001
21	60	Biased-50k	1.062e-12	1.0613e-12	-0.0007
24	100	Unbiased-100k	1.0597e-12	1.0591e-12	-0.0006
25	100	Unbiased-100k	1.0634e-12	1.063e-12	-0.0004
26	100	Unbiased-100k	1.0643e-12	1.0632e-12	-0.0011
27	100	Unbiased-100k	1.0615e-12	1.0621e-12	0.0006
28	100	Unbiased-100k	1.0614e-12	1.0615e-12	0.0001
29	110	Biased-100k	1.0606e-12	1.0593e-12	-0.0013
30	110	Biased-100k	1.0558e-12	1.0565e-12	0.0007
31	110	Biased-100k	1.0593e-12	1.0565e-12	-0.0028
32	110	Biased-100k	1.0583e-12	1.0587e-12	0.0004
34	110	Biased-100k	1.0591e-12	1.0571e-12	-0.002

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0573e-12	1.0595e-12	1.0613e-12	2.0298e-15	1.0568e-12	1.0592e-12	1.0611e-12	2.1932e-15	-0.0005	-0.0003	-0.0002	0.00017321
50	1.0575e-12	1.0612e-12	1.0658e-12	3.401e-15	1.0569e-12	1.0605e-12	1.0656e-12	3.5436e-15	-0.0029	-0.00066	0.0013	0.001511
60	1.06e-12	1.0615e-12	1.0626e-12	1.2198e-15	1.059e-12	1.0606e-12	1.0617e-12	1.1077e-15	-0.0016	-0.00088	-0.0001	0.00058481
100	1.0597e-12	1.0621e-12	1.0643e-12	1.8119e-15	1.0591e-12	1.0618e-12	1.0632e-12	1.6483e-15	-0.0011	-0.00028	0.0006	0.00065345
110	1.0558e-12	1.0586e-12	1.0606e-12	1.7796e-15	1.0565e-12	1.0576e-12	1.0593e-12	1.3008e-15	-0.0028	-0.001	0.0007	0.0015149

Device Test: 31.2 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD2/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





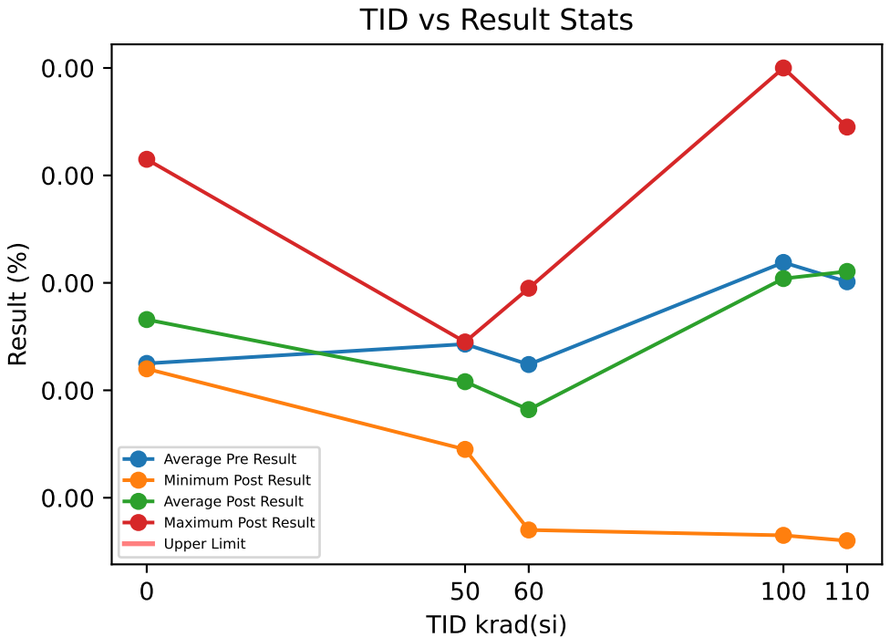
Test Results (Upper Limit = 400.0 (mV))

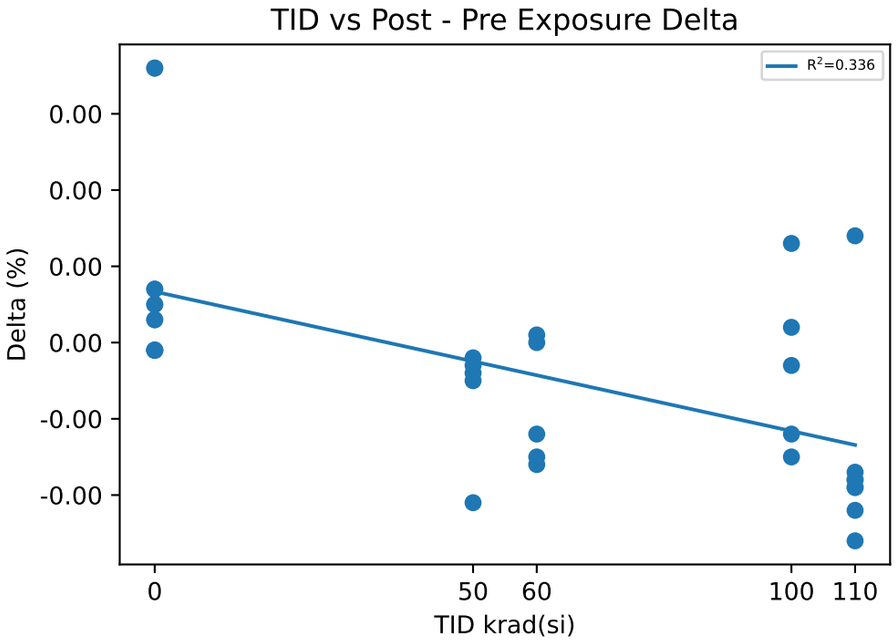
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	303.43	303.49	0.0551
2	0	CU2	301.36	301.56	0.2007
3	0	CU3	303.82	303.98	0.1615
11	50	Unbiased-50k	302.16	302.25	0.0887
12	50	Unbiased-50k	301.72	301.79	0.0697
13	50	Unbiased-50k	301.55	301.67	0.129
14	50	Unbiased-50k	302.44	302.5	0.0639
16	50	Unbiased-50k	303.85	304.05	0.196
17	60	Biased-50k	303.69	303.88	0.1927
18	60	Biased-50k	300.86	301.03	0.1755
19	60	Biased-50k	301.95	302.18	0.223
20	60	Biased-50k	301.3	301.5	0.2039
21	60	Biased-50k	304.39	304.66	0.2743
24	100	Unbiased-100k	302.64	302.3	-0.3358
25	100	Unbiased-100k	301.27	300.95	-0.3236
26	100	Unbiased-100k	301.59	301.21	-0.3804
27	100	Unbiased-100k	301.64	301.28	-0.3618
28	100	Unbiased-100k	304.19	303.93	-0.258
29	110	Biased-100k	301.63	301.49	-0.1406
30	110	Biased-100k	304.17	304.1	-0.071
31	110	Biased-100k	302.67	302.54	-0.1271
32	110	Biased-100k	300.34	301.37	1.0337
34	110	Biased-100k	303.07	302.94	-0.131

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	301.36	302.87	303.82	1.3212	301.56	303.01	303.98	1.2777	0.0551	0.1391	0.2007	0.07534
50	301.55	302.34	303.85	0.91397	301.67	302.45	304.05	0.95288	0.0639	0.10946	0.196	0.054678
60	300.86	302.44	304.39	1.5334	301.03	302.65	304.66	1.5596	0.1755	0.21388	0.2743	0.037931
100	301.27	302.27	304.19	1.1898	300.95	301.93	303.93	1.2286	-0.3804	-0.33192	-0.258	0.046882
110	300.34	302.37	304.17	1.4577	301.37	302.49	304.1	1.1234	-0.1406	0.1128	1.0337	0.51552

st: 31.20 VSENSE_VTH_FALLING_GOOD(PWRGD|FallingGood/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_FALLIN





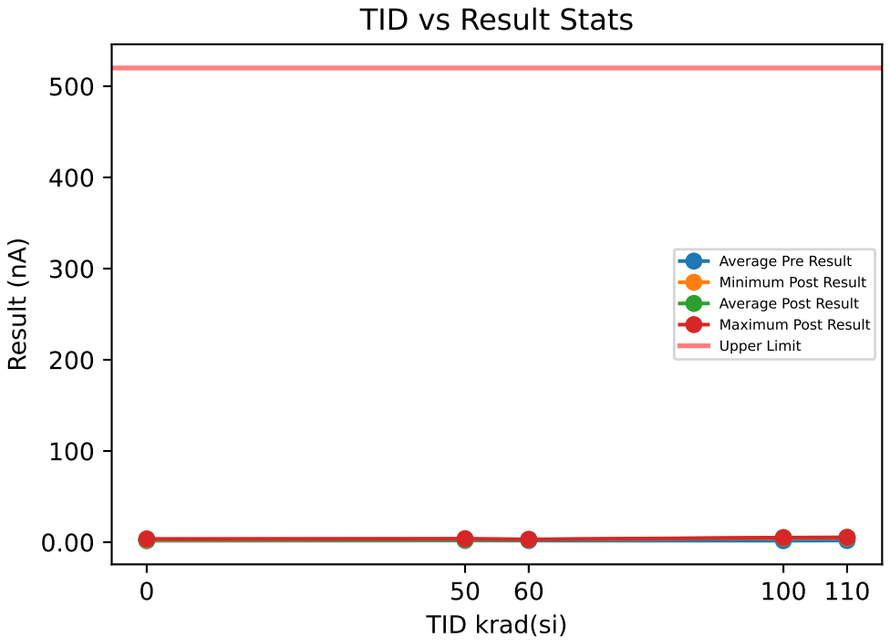
Test Results (No Limits Specified (%))

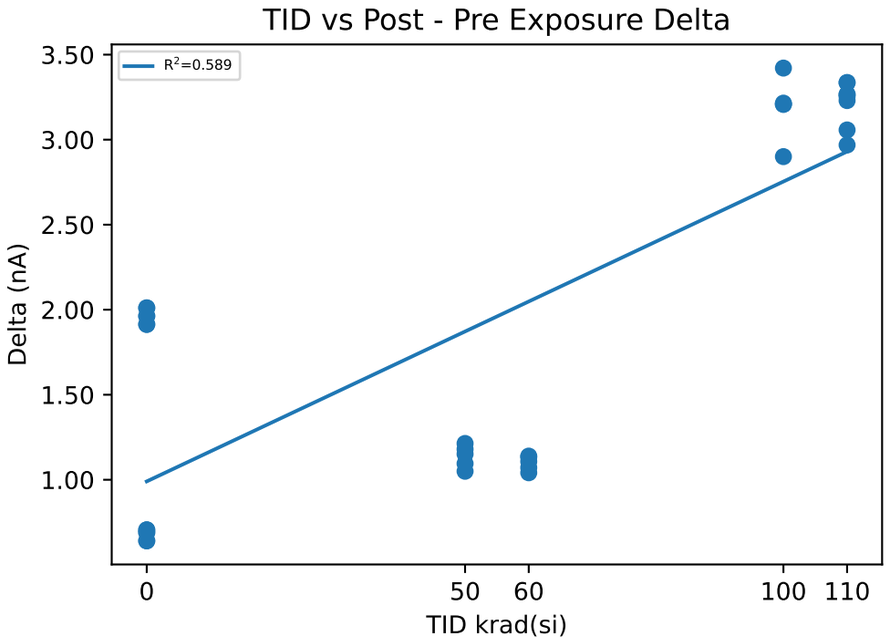
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0607e-12	1.0606e-12	-0.0001
2	0	CU2	1.0607e-12	1.0606e-12	-0.0001
3	0	CU3	1.0601e-12	1.0604e-12	0.0003
11	50	Unbiased-50k	1.0627e-12	1.0606e-12	-0.0021
12	50	Unbiased-50k	1.0591e-12	1.0589e-12	-0.0002
13	50	Unbiased-50k	1.0613e-12	1.0609e-12	-0.0004
14	50	Unbiased-50k	1.0609e-12	1.0604e-12	-0.0005
16	50	Unbiased-50k	1.0603e-12	1.06e-12	-0.0003
17	60	Biased-50k	1.0601e-12	1.0589e-12	-0.0012
18	60	Biased-50k	1.0612e-12	1.0596e-12	-0.0016
19	60	Biased-50k	1.0589e-12	1.0574e-12	-0.0015
20	60	Biased-50k	1.0604e-12	1.0604e-12	0
21	60	Biased-50k	1.0618e-12	1.0619e-12	0.0001
24	100	Unbiased-100k	1.0627e-12	1.0612e-12	-0.0015
25	100	Unbiased-100k	1.0585e-12	1.0573e-12	-0.0012
26	100	Unbiased-100k	1.0663e-12	1.066e-12	-0.0003
27	100	Unbiased-100k	1.0641e-12	1.0654e-12	0.0013
28	100	Unbiased-100k	1.0603e-12	1.0605e-12	0.0002
29	110	Biased-100k	1.0594e-12	1.0572e-12	-0.0022
30	110	Biased-100k	1.0607e-12	1.059e-12	-0.0017
31	110	Biased-100k	1.0619e-12	1.0593e-12	-0.0026
32	110	Biased-100k	1.0614e-12	1.0628e-12	0.0014
34	110	Biased-100k	1.0667e-12	1.0648e-12	-0.0019

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0601e-12	1.0605e-12	1.0607e-12	3.4641e-16	1.0604e-12	1.0605e-12	1.0606e-12	1.1547e-16	-0.0001	3.3333e-05	0.0003	0.00023094
50	1.0591e-12	1.0609e-12	1.0627e-12	1.3221e-15	1.0589e-12	1.0602e-12	1.0609e-12	7.7653e-16	-0.0021	-0.0007	-0.0002	0.00079057
60	1.0589e-12	1.0605e-12	1.0618e-12	1.1077e-15	1.0574e-12	1.0596e-12	1.0619e-12	1.6772e-15	-0.0016	-0.00084	0.0001	0.00082644
100	1.0585e-12	1.0624e-12	1.0663e-12	3.0744e-15	1.0573e-12	1.0621e-12	1.066e-12	3.6231e-15	-0.0015	-0.0003	0.0013	0.0011247
110	1.0594e-12	1.062e-12	1.0667e-12	2.7797e-15	1.0572e-12	1.0606e-12	1.0648e-12	3.0939e-15	-0.0026	-0.0014	0.0014	0.0016016

st: 31.21 PWRGD_OUTPUT_HIGH_LEAK(PWRGD|LeakageHigh/PWRGD1/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HI





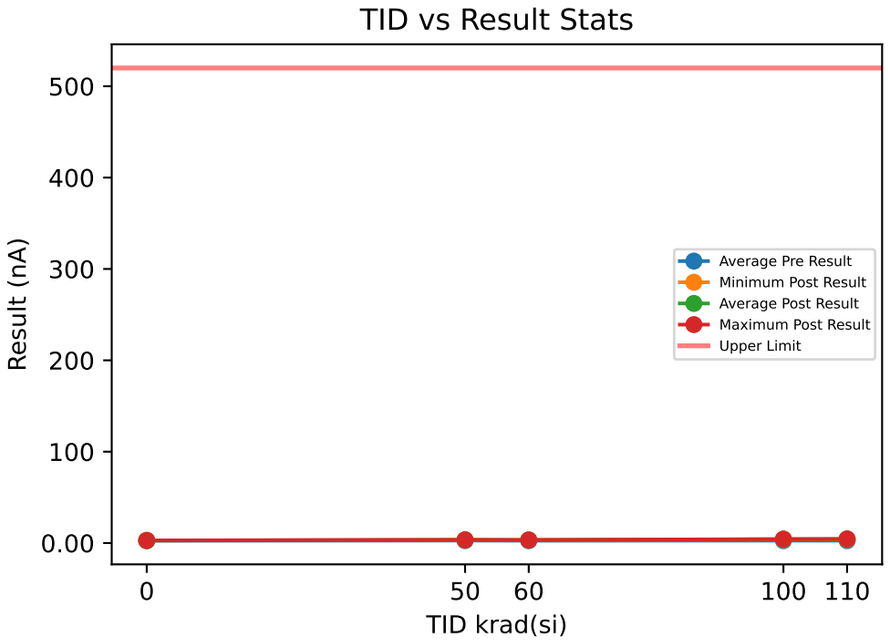
Test Results (Upper Limit = 520.0 (nA))

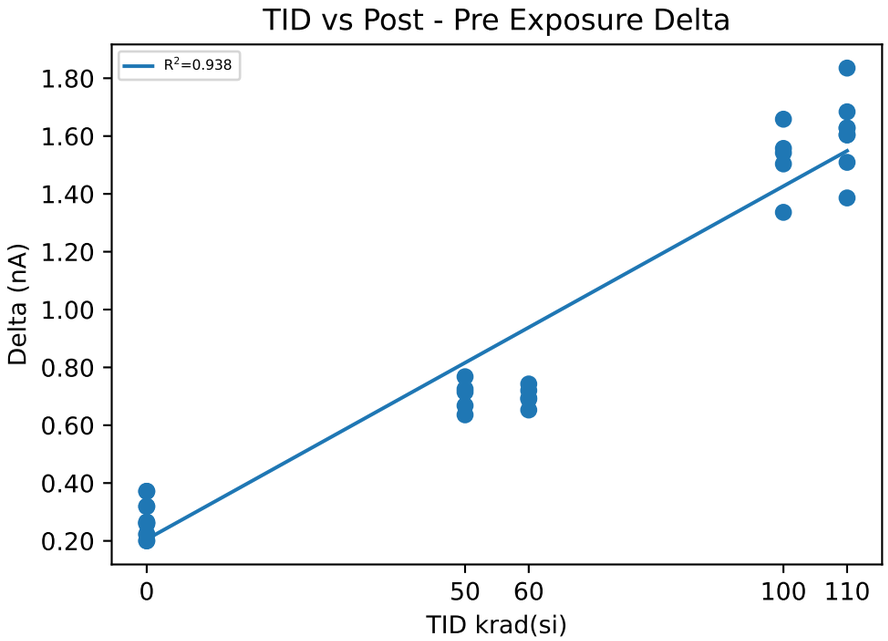
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.6156	2.3053	0.6897
2	0	CU2	1.6581	2.299	0.6409
3	0	CU3	1.6112	2.3165	0.7053
11	50	Unbiased-50k	1.67	2.72	1.05
12	50	Unbiased-50k	2.6548	3.8682	1.2134
13	50	Unbiased-50k	1.6826	2.8337	1.1511
14	50	Unbiased-50k	1.6481	2.8275	1.1794
16	50	Unbiased-50k	1.6231	2.7182	1.0951
17	60	Biased-50k	1.7076	2.7488	1.0412
18	60	Biased-50k	1.6519	2.7856	1.1337
19	60	Biased-50k	2.0338	3.1729	1.1391
20	60	Biased-50k	1.6988	2.8063	1.1075
21	60	Biased-50k	1.6719	2.7432	1.0713
24	100	Unbiased-100k	1.6431	4.8512	3.2081
25	100	Unbiased-100k	1.6957	4.9036	3.2079
26	100	Unbiased-100k	1.6531	5.0741	3.421
27	100	Unbiased-100k	1.6657	4.8805	3.2148
28	100	Unbiased-100k	1.6231	4.5234	2.9003
29	110	Biased-100k	1.7846	5.0385	3.2539
30	110	Biased-100k	1.6694	4.6383	2.9689
31	110	Biased-100k	1.6531	4.883	3.2299
32	110	Biased-100k	2.0838	5.1409	3.0571
34	110	Biased-100k	2.0319	5.3675	3.3356

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6112	1.6283	1.6581	0.025901	2.299	2.3069	2.3165	0.0088636	0.6409	0.67863	0.7053	0.033596
50	1.6231	1.8557	2.6548	0.44727	2.7182	2.9935	3.8682	0.49213	1.05	1.1378	1.2134	0.065488
60	1.6519	1.7528	2.0338	0.15862	2.7432	2.8514	3.1729	0.18163	1.0412	1.0986	1.1391	0.041808
100	1.6231	1.6561	1.6957	0.027052	4.5234	4.8466	5.0741	0.2004	2.9003	3.1904	3.421	0.18611
110	1.6531	1.8446	2.0838	0.20203	4.6383	5.0136	5.3675	0.27385	2.9689	3.1691	3.3356	0.15102

st: 31.22 PWRGD_OUTPUT_HIGH_LEAK(PWRGD|LeakageHigh/PWRGD2/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HI





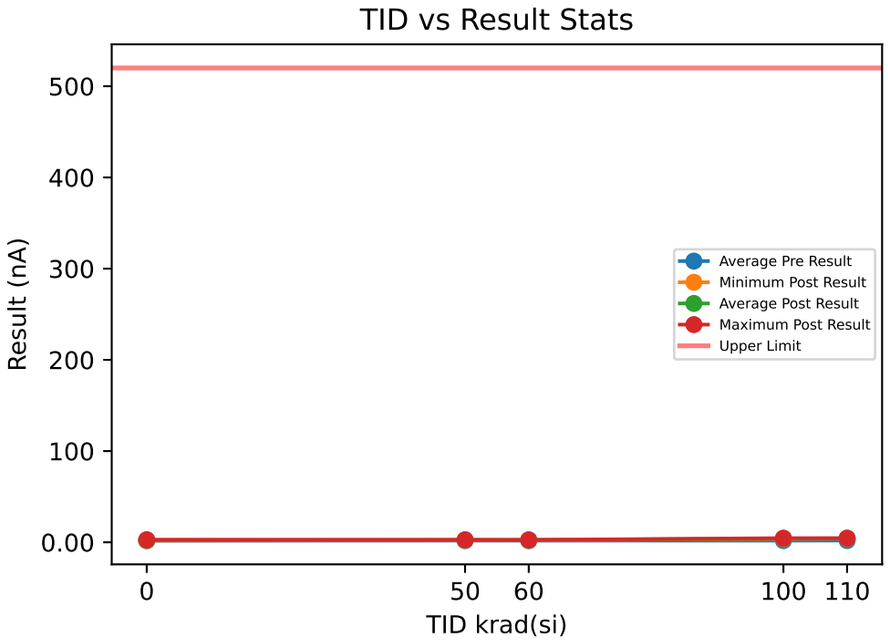
Test Results (Upper Limit = 520.0 (nA))

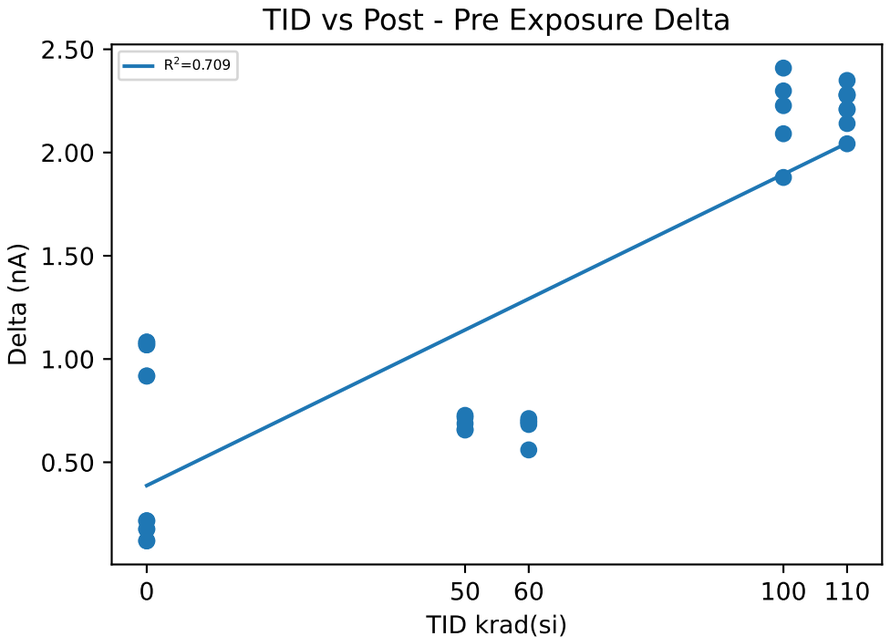
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5869	2.7871	0.2002
2	0	CU2	2.5363	2.759	0.2227
3	0	CU3	2.4933	2.7527	0.2594
11	50	Unbiased-50k	2.6574	3.3251	0.6677
12	50	Unbiased-50k	2.6661	3.4338	0.7677
13	50	Unbiased-50k	2.7117	3.4263	0.7146
14	50	Unbiased-50k	2.7772	3.5024	0.7252
16	50	Unbiased-50k	2.6056	3.2415	0.6359
17	60	Biased-50k	2.4845	3.2271	0.7426
18	60	Biased-50k	2.6362	3.2889	0.6527
19	60	Biased-50k	2.5744	3.2946	0.7202
20	60	Biased-50k	2.6156	3.3058	0.6902
21	60	Biased-50k	2.5039	3.1978	0.6939
24	100	Unbiased-100k	2.7972	4.3008	1.5036
25	100	Unbiased-100k	2.6093	4.1665	1.5572
26	100	Unbiased-100k	2.6443	4.3026	1.6583
27	100	Unbiased-100k	2.6318	4.174	1.5422
28	100	Unbiased-100k	2.5238	3.86	1.3362
29	110	Biased-100k	2.6911	4.375	1.6839
30	110	Biased-100k	2.5145	3.9005	1.386
31	110	Biased-100k	2.6281	4.1372	1.5091
32	110	Biased-100k	2.6199	4.455	1.8351
34	110	Biased-100k	2.7535	4.3813	1.6278

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4933	2.5388	2.5869	0.046851	2.7527	2.7663	2.7871	0.018315	0.2002	0.22743	0.2594	0.029882
50	2.6056	2.6836	2.7772	0.064473	3.2415	3.3858	3.5024	0.10253	0.6359	0.70222	0.7677	0.051378
60	2.4845	2.5629	2.6362	0.066914	3.1978	3.2628	3.3058	0.047542	0.6527	0.69992	0.7426	0.033887
100	2.5238	2.6413	2.7972	0.099038	3.86	4.1608	4.3026	0.18055	1.3362	1.5195	1.6583	0.11732
110	2.5145	2.6414	2.7535	0.089134	3.9005	4.2498	4.455	0.229	1.386	1.6084	1.8351	0.17087

st: 31.23 PWRGD_OUTPUT_HIGH_LEAK(PWRGD|LeakageHigh/PWRGD3/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HI





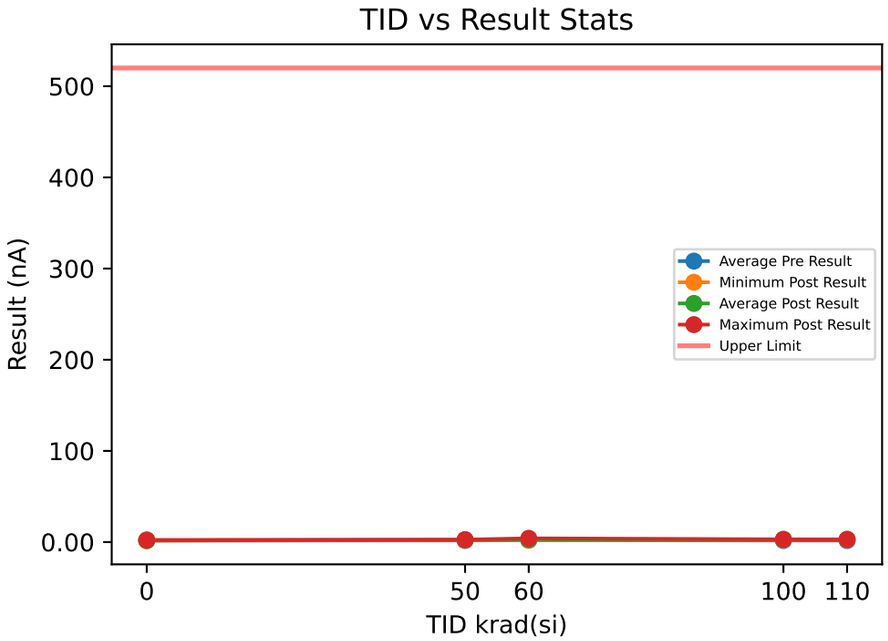
Test Results (Upper Limit = 520.0 (nA))

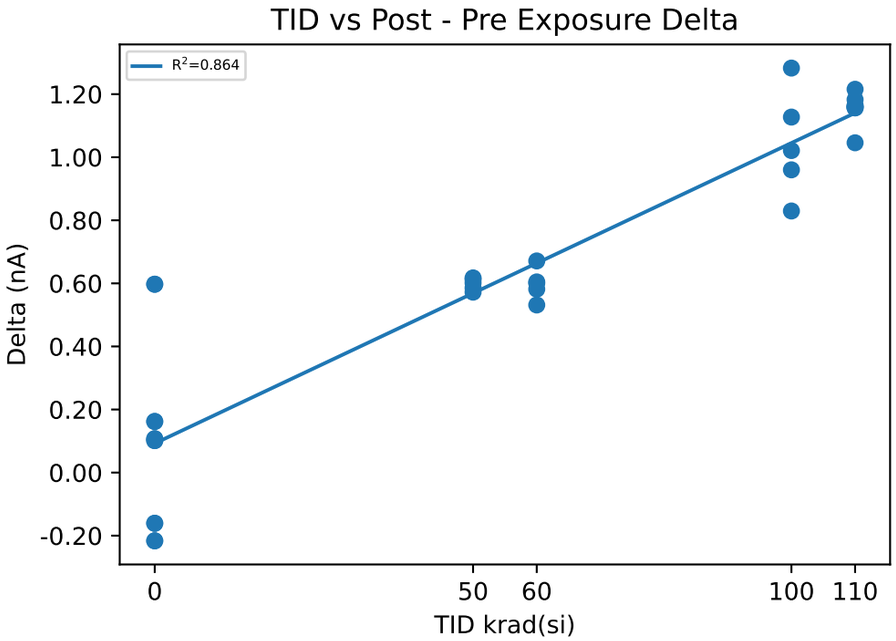
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.6778	1.8541	0.1763
2	0	CU2	1.7415	1.958	0.2165
3	0	CU3	1.7627	1.8823	0.1196
11	50	Unbiased-50k	1.8171	2.4734	0.6563
12	50	Unbiased-50k	1.7746	2.4621	0.6875
13	50	Unbiased-50k	1.842	2.5691	0.7271
14	50	Unbiased-50k	1.8296	2.5466	0.717
16	50	Unbiased-50k	2.0125	2.6717	0.6592
17	60	Biased-50k	1.8427	2.5365	0.6938
18	60	Biased-50k	1.7634	2.4634	0.7
19	60	Biased-50k	1.9095	2.621	0.7115
20	60	Biased-50k	1.7684	2.4515	0.6831
21	60	Biased-50k	1.7527	2.3126	0.5599
24	100	Unbiased-100k	1.784	3.875	2.091
25	100	Unbiased-100k	1.8264	4.1248	2.2984
26	100	Unbiased-100k	2.123	4.532	2.409
27	100	Unbiased-100k	1.8308	4.058	2.2272
28	100	Unbiased-100k	1.789	3.6683	1.8793
29	110	Biased-100k	1.8383	4.1204	2.2821
30	110	Biased-100k	1.7771	3.9175	2.1404
31	110	Biased-100k	1.8008	4.1498	2.349
32	110	Biased-100k	2.0706	4.113	2.0424
34	110	Biased-100k	2.2086	4.4858	2.2772

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6778	1.7273	1.7627	0.044187	1.8541	1.8981	1.958	0.053729	0.1196	0.1708	0.2165	0.048684
50	1.7746	1.8552	2.0125	0.091544	2.4621	2.5446	2.6717	0.084608	0.6563	0.68942	0.7271	0.032382
60	1.7527	1.8073	1.9095	0.067304	2.3126	2.477	2.621	0.11417	0.5599	0.66966	0.7115	0.062213
100	1.784	1.8706	2.123	0.14265	3.6683	4.0516	4.532	0.32183	1.8793	2.181	2.409	0.20434
110	1.7771	1.9391	2.2086	0.19069	3.9175	4.1573	4.4858	0.20542	2.0424	2.2182	2.349	0.12413

st: 31.24 PWRGD_OUTPUT_HIGH_LEAK(PWRGD|LeakageHigh/PWRGD4/7/7///90.9/634//1.8///@PWRGD_OUTPUT_HI





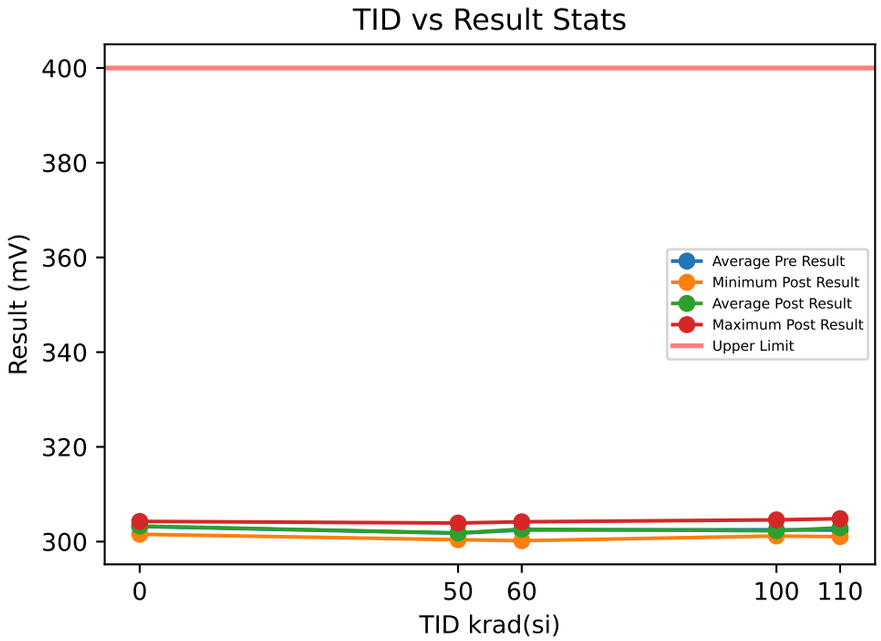
Test Results (Upper Limit = 520.0 (nA))

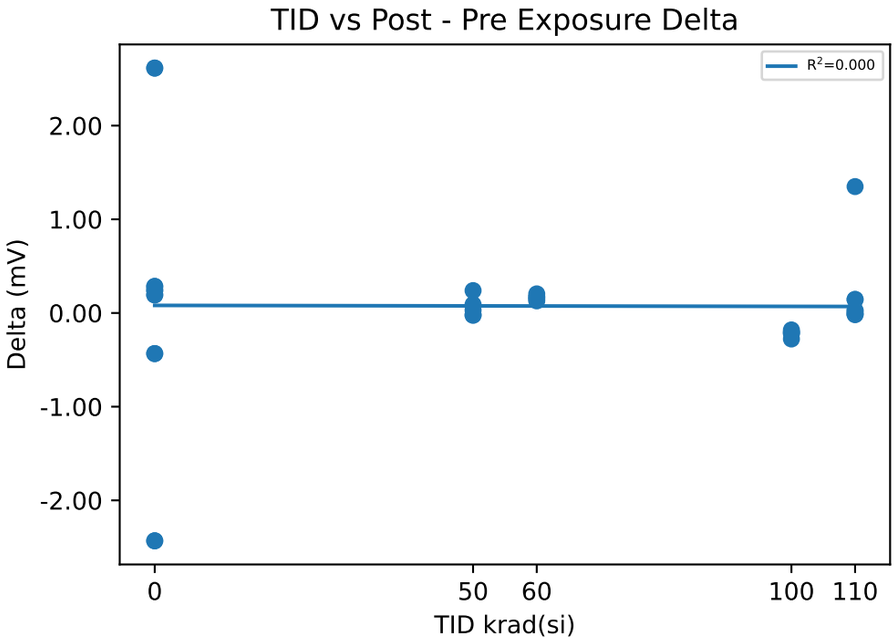
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.7236	1.8308	0.1072
2	0	CU2	1.7019	1.8033	0.1014
3	0	CU3	1.6651	1.8271	0.162
11	50	Unbiased-50k	2.0716	2.6732	0.6016
12	50	Unbiased-50k	1.7436	2.3291	0.5855
13	50	Unbiased-50k	1.7535	2.3709	0.6174
14	50	Unbiased-50k	1.6626	2.2754	0.6128
16	50	Unbiased-50k	1.6377	2.2098	0.5721
17	60	Biased-50k	1.6633	2.2679	0.6046
18	60	Biased-50k	3.4313	4.1024	0.6711
19	60	Biased-50k	1.7118	2.3122	0.6004
20	60	Biased-50k	1.9017	2.4833	0.5816
21	60	Biased-50k	1.6178	2.1493	0.5315
24	100	Unbiased-100k	1.6981	2.6581	0.96
25	100	Unbiased-100k	1.7137	2.841	1.1273
26	100	Unbiased-100k	1.7187	3.0014	1.2827
27	100	Unbiased-100k	1.7361	2.7573	1.0212
28	100	Unbiased-100k	1.7218	2.5513	0.8295
29	110	Biased-100k	1.6608	2.8254	1.1646
30	110	Biased-100k	1.6222	2.668	1.0458
31	110	Biased-100k	1.6782	2.861	1.1828
32	110	Biased-100k	1.7641	2.9796	1.2155
34	110	Biased-100k	1.6956	2.856	1.1604

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6651	1.6969	1.7236	0.029573	1.8033	1.8204	1.8308	0.014924	0.1014	0.12353	0.162	0.033439
50	1.6377	1.7738	2.0716	0.17385	2.2098	2.3717	2.6732	0.17903	0.5721	0.59788	0.6174	0.018943
60	1.6178	2.0652	3.4313	0.77129	2.1493	2.663	4.1024	0.81351	0.5315	0.59784	0.6711	0.05021
100	1.6981	1.7177	1.7361	0.013753	2.5513	2.7618	3.0014	0.17231	0.8295	1.0441	1.2827	0.17139
110	1.6222	1.6842	1.7641	0.052301	2.668	2.838	2.9796	0.11176	1.0458	1.1538	1.2155	0.064172

Device Test: 31.3 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD3/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





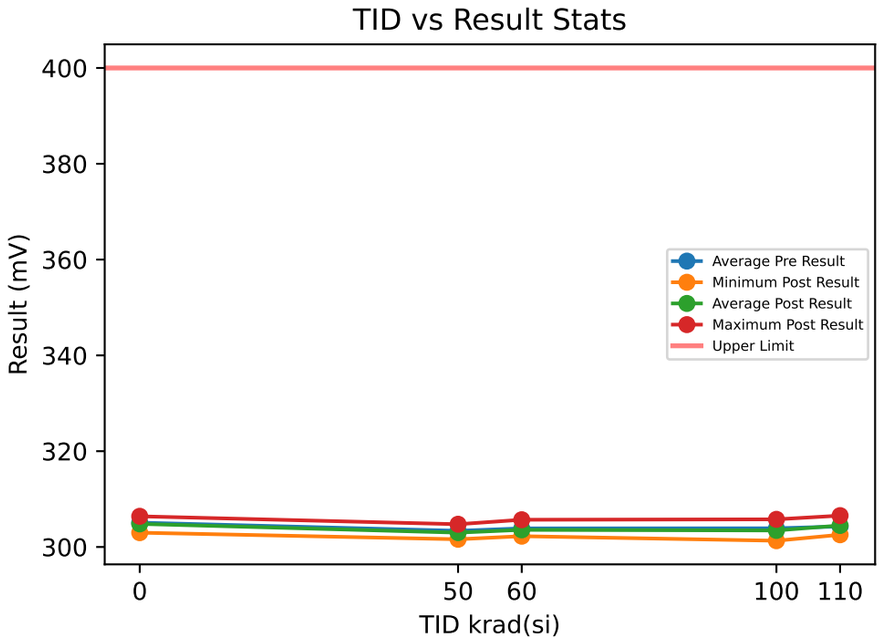
Test Results (Upper Limit = 400.0 (mV))

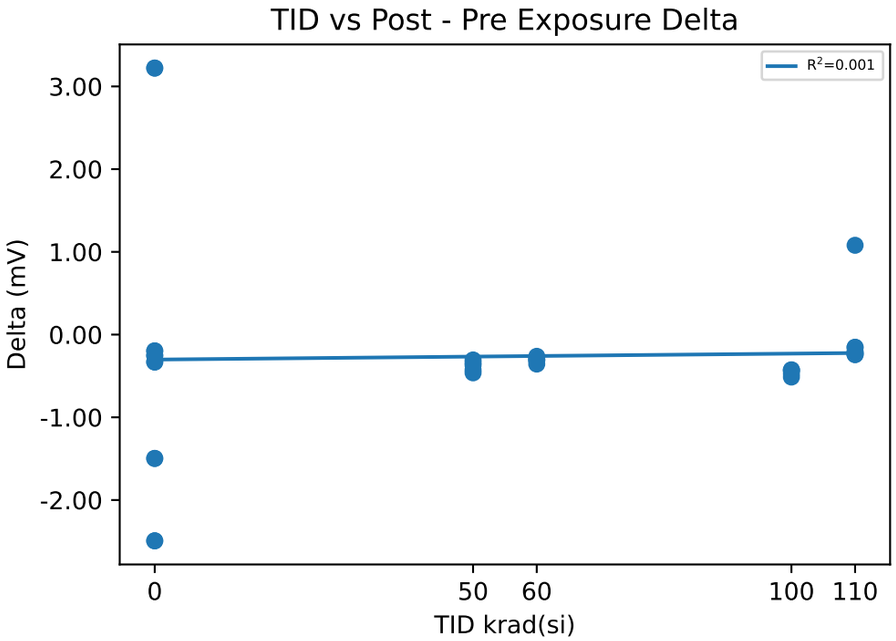
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	304.07	304.26	0.193
2	0	CU2	301.55	301.79	0.2418
3	0	CU3	303.98	304.26	0.2835
11	50	Unbiased-50k	301.28	301.25	-0.0246
12	50	Unbiased-50k	300.41	300.39	-0.0198
13	50	Unbiased-50k	300.66	300.69	0.0307
14	50	Unbiased-50k	302.77	302.86	0.0906
16	50	Unbiased-50k	303.68	303.92	0.2392
17	60	Biased-50k	303.47	303.6	0.1294
18	60	Biased-50k	300.01	300.18	0.1735
19	60	Biased-50k	303.41	303.58	0.1668
20	60	Biased-50k	301.32	301.52	0.2039
21	60	Biased-50k	304.03	304.18	0.1459
24	100	Unbiased-100k	302.28	302.01	-0.2775
25	100	Unbiased-100k	301.36	301.18	-0.1808
26	100	Unbiased-100k	301.87	301.67	-0.2026
27	100	Unbiased-100k	302.18	301.97	-0.2119
28	100	Unbiased-100k	304.81	304.59	-0.2208
29	110	Biased-100k	302.02	302	-0.0183
30	110	Biased-100k	304.81	304.84	0.026
31	110	Biased-100k	301.02	301.05	0.0253
32	110	Biased-100k	301.04	302.39	1.3493
34	110	Biased-100k	303.2	303.19	-0.0087

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	301.55	303.2	304.07	1.4312	301.79	303.44	304.26	1.4284	0.193	0.23943	0.2835	0.045296
50	300.41	301.76	303.68	1.4094	300.39	301.82	303.92	1.5085	-0.0246	0.06322	0.2392	0.10884
60	300.01	302.45	304.03	1.7101	300.18	302.61	304.18	1.6913	0.1294	0.1639	0.2039	0.02835
100	301.36	302.5	304.81	1.3379	301.18	302.28	304.59	1.3295	-0.2775	-0.21872	-0.1808	0.036068
110	301.02	302.42	304.81	1.6083	301.05	302.69	304.84	1.4254	-0.0183	0.27472	1.3493	0.60104

Device Test: 31.4 PWRGD_OUTPUT_LOW(PWRGD|VOL/PWRGD4/7/7///90.9/634//1.8///@PWRGD_OUTPUT_LOW)





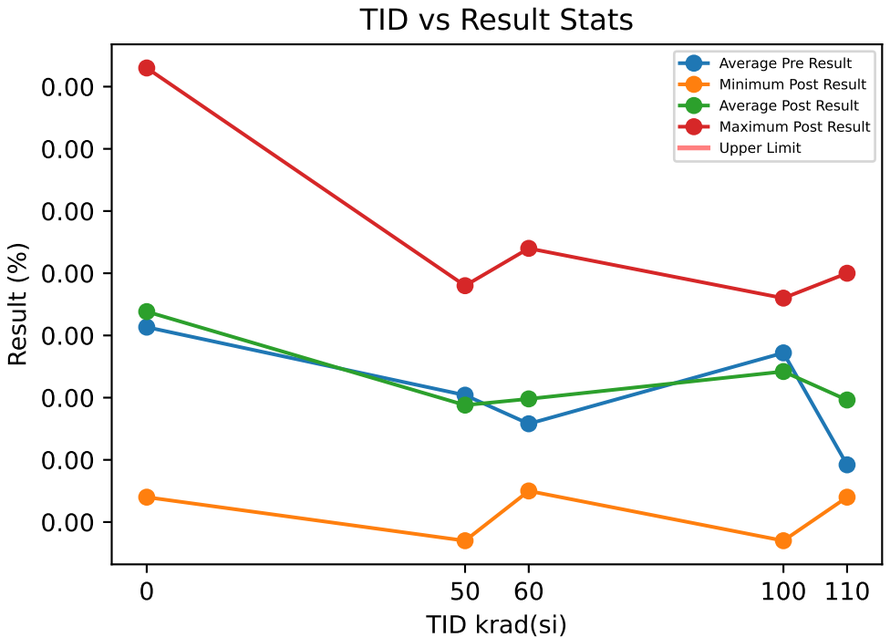
Test Results (Upper Limit = 400.0 (mV))

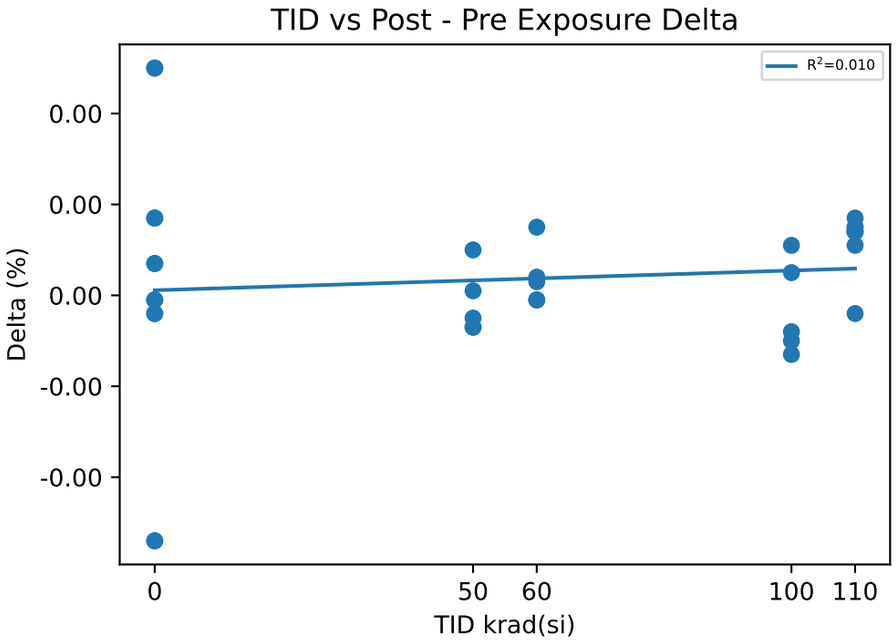
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	306.52	306.19	-0.3315
2	0	CU2	303.18	302.99	-0.1971
3	0	CU3	305.53	305.28	-0.2534
11	50	Unbiased-50k	302.74	302.31	-0.4282
12	50	Unbiased-50k	302.08	301.61	-0.4625
13	50	Unbiased-50k	303.26	302.92	-0.3407
14	50	Unbiased-50k	303.75	303.38	-0.3689
16	50	Unbiased-50k	305.06	304.75	-0.3064
17	60	Biased-50k	304.4	304.04	-0.3564
18	60	Biased-50k	302.56	302.26	-0.3064
19	60	Biased-50k	303.91	303.59	-0.3127
20	60	Biased-50k	302.57	302.31	-0.2627
21	60	Biased-50k	305.98	305.69	-0.294
24	100	Unbiased-100k	303.76	303.25	-0.5132
25	100	Unbiased-100k	301.74	301.31	-0.4258
26	100	Unbiased-100k	303.62	303.15	-0.4726
27	100	Unbiased-100k	304.21	303.78	-0.4289
28	100	Unbiased-100k	306.21	305.77	-0.4351
29	110	Biased-100k	304.49	304.26	-0.2321
30	110	Biased-100k	306.76	306.55	-0.2165
31	110	Biased-100k	302.76	302.56	-0.2072
32	110	Biased-100k	302.45	303.53	1.0795
34	110	Biased-100k	304.96	304.72	-0.2415

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	303.18	305.08	306.52	1.7146	302.99	304.82	306.19	1.6508	-0.3315	-0.26067	-0.1971	0.067494
50	302.08	303.38	305.06	1.1265	301.61	303	304.75	1.1848	-0.4625	-0.38134	-0.3064	0.06365
60	302.56	303.88	305.98	1.4261	302.26	303.58	305.69	1.4165	-0.3564	-0.30644	-0.2627	0.033923
100	301.74	303.91	306.21	1.5969	301.31	303.45	305.77	1.598	-0.5132	-0.45512	-0.4258	0.037506
110	302.45	304.29	306.76	1.7553	302.56	304.32	306.55	1.4883	-0.2415	0.03644	1.0795	0.58324

Test: 31.5 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING





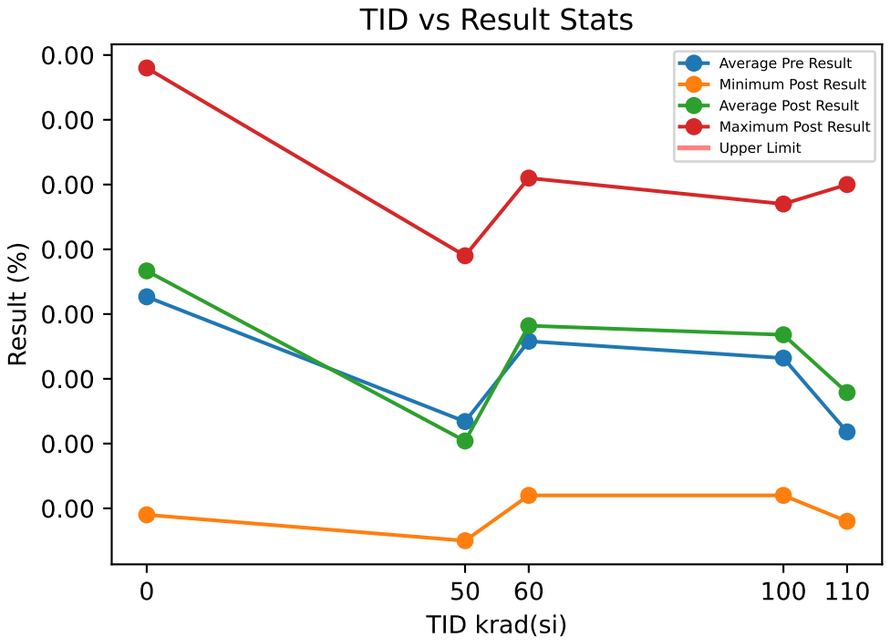
Test Results (No Limits Specified (%))

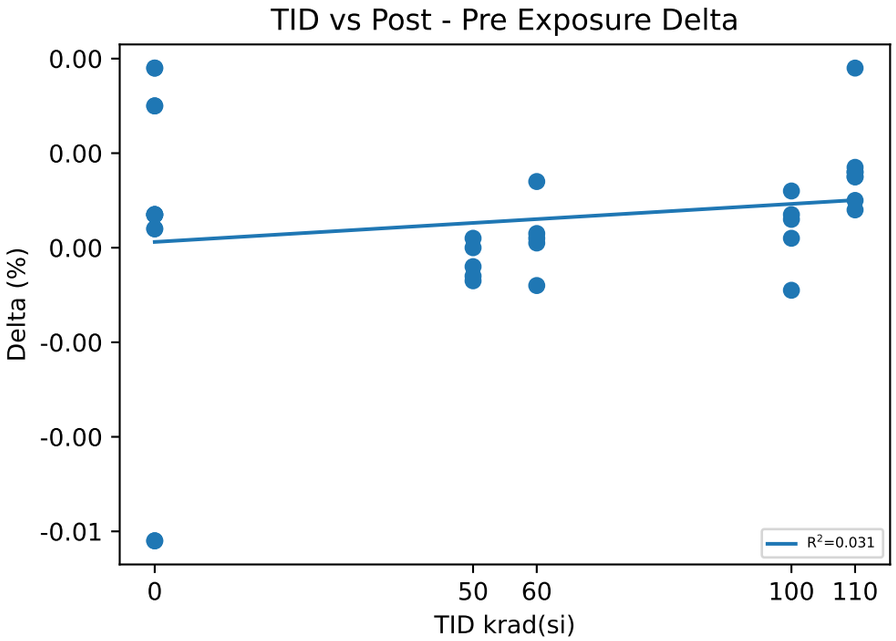
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.065e-13	9.064e-13	-0.0001
2	0	CU2	9.126e-13	9.133e-13	0.0007
3	0	CU3	9.083e-13	9.079e-13	-0.0004
11	50	Unbiased-50k	9.088e-13	9.098e-13	0.001
12	50	Unbiased-50k	9.064e-13	9.057e-13	-0.0007
13	50	Unbiased-50k	9.084e-13	9.085e-13	0.0001
14	50	Unbiased-50k	9.087e-13	9.08e-13	-0.0007
16	50	Unbiased-50k	9.079e-13	9.074e-13	-0.0005
17	60	Biased-50k	9.079e-13	9.078e-13	-0.0001
18	60	Biased-50k	9.069e-13	9.072e-13	0.0003
19	60	Biased-50k	9.076e-13	9.08e-13	0.0004
20	60	Biased-50k	9.066e-13	9.065e-13	-0.0001
21	60	Biased-50k	9.089e-13	9.104e-13	0.0015
24	100	Unbiased-100k	9.067e-13	9.057e-13	-0.001
25	100	Unbiased-100k	9.099e-13	9.086e-13	-0.0013
26	100	Unbiased-100k	9.085e-13	9.096e-13	0.0011
27	100	Unbiased-100k	9.087e-13	9.092e-13	0.0005
28	100	Unbiased-100k	9.098e-13	9.09e-13	-0.0008
29	110	Biased-100k	9.055e-13	9.069e-13	0.0014
30	110	Biased-100k	9.104e-13	9.1e-13	-0.0004
31	110	Biased-100k	9.069e-13	9.086e-13	0.0017
32	110	Biased-100k	9.053e-13	9.064e-13	0.0011
34	110	Biased-100k	9.065e-13	9.079e-13	0.0014

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.065e-13	9.0913e-13	9.126e-13	3.1342e-15	9.064e-13	9.092e-13	9.133e-13	3.629e-15	-0.0004	6.6667e-05	0.0007	0.00056862
50	9.064e-13	9.0804e-13	9.088e-13	9.8133e-16	9.057e-13	9.0788e-13	9.098e-13	1.5057e-15	-0.0007	-0.00016	0.001	0.00072664
60	9.066e-13	9.0758e-13	9.089e-13	9.0388e-16	9.065e-13	9.0798e-13	9.104e-13	1.4738e-15	-0.0001	0.0004	0.0015	0.00065574
100	9.067e-13	9.0872e-13	9.099e-13	1.2931e-15	9.057e-13	9.0842e-13	9.096e-13	1.5627e-15	-0.0013	-0.0003	0.0011	0.0010416
110	9.053e-13	9.0692e-13	9.104e-13	2.0572e-15	9.064e-13	9.0796e-13	9.1e-13	1.4258e-15	-0.0004	0.00104	0.0017	0.00083247

Test: 31.6 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD2/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING





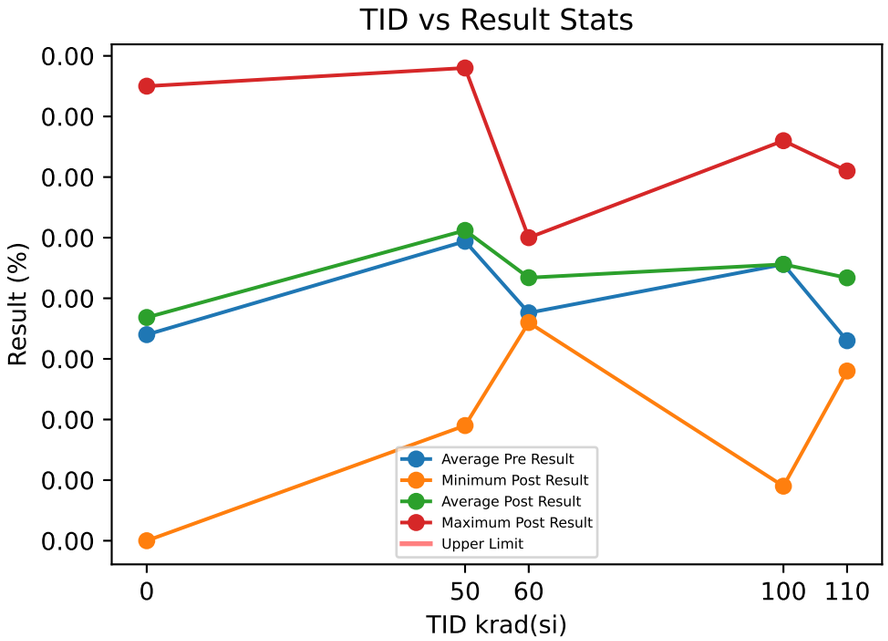
Test Results (No Limits Specified (%))

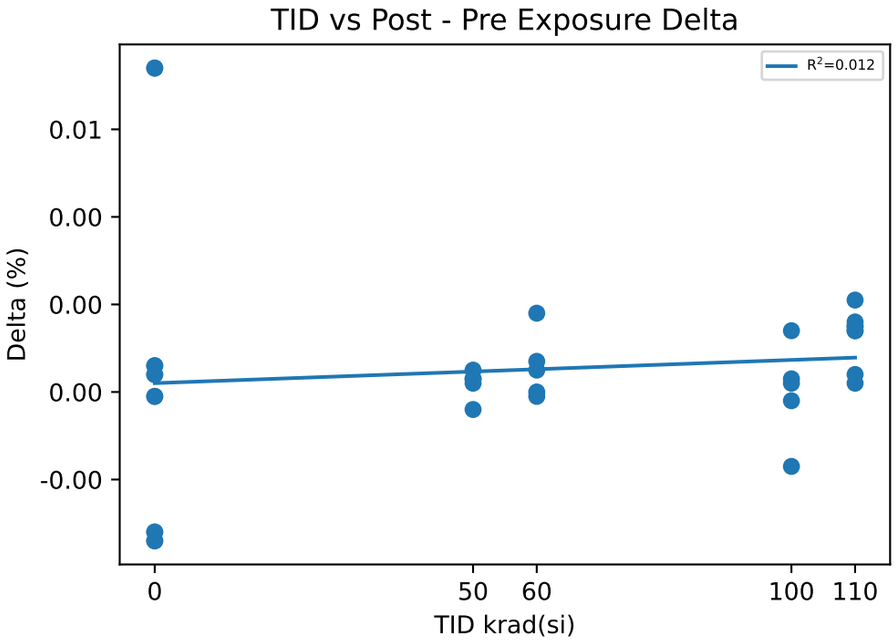
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.121e-13	9.128e-13	0.0007
2	0	CU2	9.09e-13	9.097e-13	0.0007
3	0	CU3	9.067e-13	9.071e-13	0.0004
11	50	Unbiased-50k	9.099e-13	9.099e-13	0
12	50	Unbiased-50k	9.057e-13	9.059e-13	0.0002
13	50	Unbiased-50k	9.077e-13	9.071e-13	-0.0006
14	50	Unbiased-50k	9.075e-13	9.068e-13	-0.0007
16	50	Unbiased-50k	9.059e-13	9.055e-13	-0.0004
17	60	Biased-50k	9.07e-13	9.062e-13	-0.0008
18	60	Biased-50k	9.093e-13	9.095e-13	0.0002
19	60	Biased-50k	9.061e-13	9.064e-13	0.0003
20	60	Biased-50k	9.108e-13	9.109e-13	0.0001
21	60	Biased-50k	9.097e-13	9.111e-13	0.0014
24	100	Unbiased-100k	9.067e-13	9.074e-13	0.0007
25	100	Unbiased-100k	9.095e-13	9.107e-13	0.0012
26	100	Unbiased-100k	9.102e-13	9.104e-13	0.0002
27	100	Unbiased-100k	9.081e-13	9.087e-13	0.0006
28	100	Unbiased-100k	9.071e-13	9.062e-13	-0.0009
29	110	Biased-100k	9.072e-13	9.11e-13	0.0038
30	110	Biased-100k	9.062e-13	9.072e-13	0.001
31	110	Biased-100k	9.095e-13	9.103e-13	0.0008
32	110	Biased-100k	9.087e-13	9.104e-13	0.0017
34	110	Biased-100k	9.043e-13	9.058e-13	0.0015

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.067e-13	9.0927e-13	9.121e-13	2.7099e-15	9.071e-13	9.0987e-13	9.128e-13	2.8537e-15	0.0004	0.0006	0.0007	0.00017321
50	9.057e-13	9.0734e-13	9.099e-13	1.6935e-15	9.055e-13	9.0704e-13	9.099e-13	1.7257e-15	-0.0007	-0.0003	0.0002	0.0003873
60	9.061e-13	9.0858e-13	9.108e-13	1.9588e-15	9.062e-13	9.0882e-13	9.111e-13	2.3826e-15	-0.0008	0.00024	0.0014	0.00078294
100	9.067e-13	9.0832e-13	9.102e-13	1.5073e-15	9.062e-13	9.0868e-13	9.107e-13	1.9254e-15	-0.0009	0.00036	0.0012	0.0007893
110	9.043e-13	9.0718e-13	9.095e-13	2.0584e-15	9.058e-13	9.0894e-13	9.11e-13	2.2974e-15	0.0008	0.00176	0.0038	0.0011971

Test: 31.7 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD3/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING





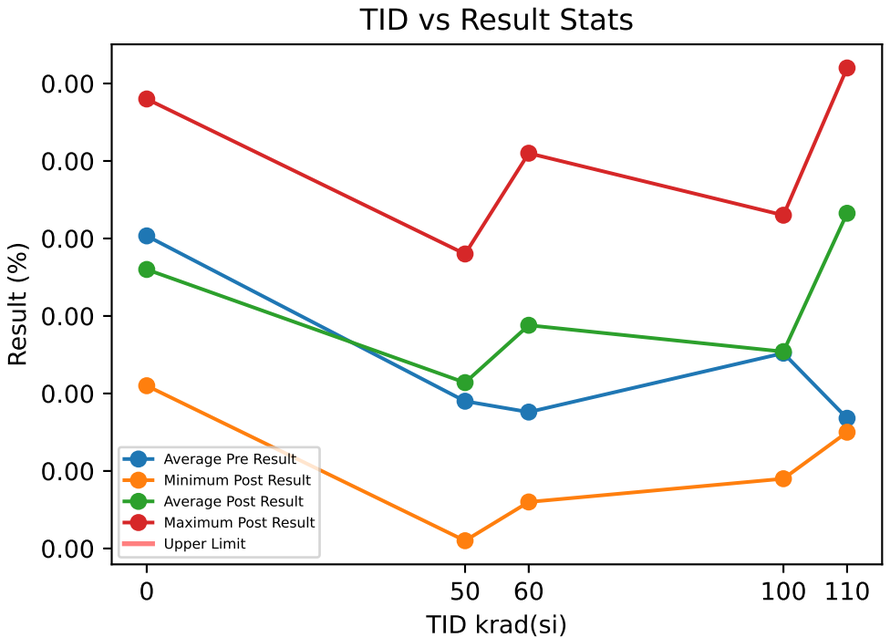
Test Results (No Limits Specified (%))

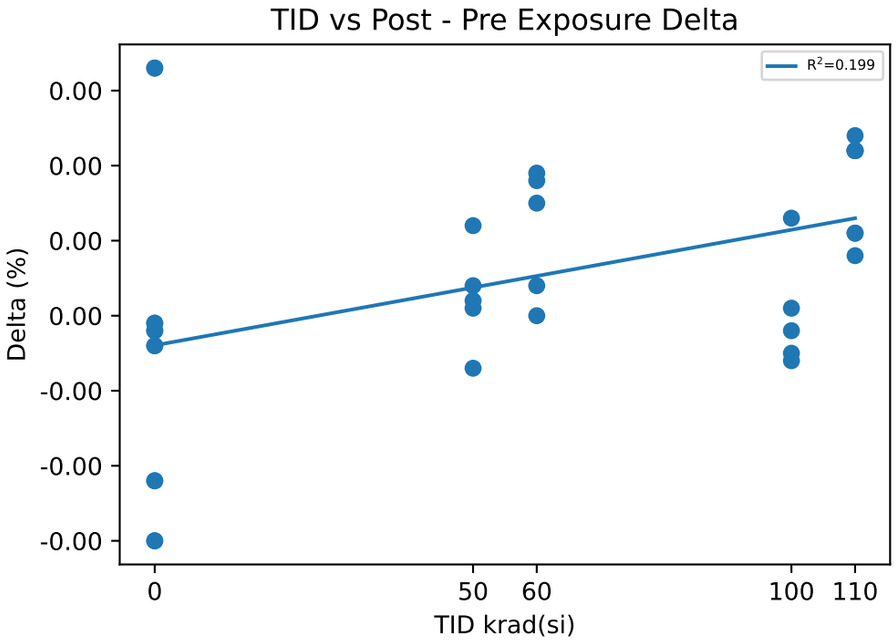
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.109e-13	9.115e-13	0.0006
2	0	CU2	9.041e-13	9.04e-13	-0.0001
3	0	CU3	9.072e-13	9.076e-13	0.0004
11	50	Unbiased-50k	9.056e-13	9.059e-13	0.0003
12	50	Unbiased-50k	9.104e-13	9.1e-13	-0.0004
13	50	Unbiased-50k	9.07e-13	9.073e-13	0.0003
14	50	Unbiased-50k	9.104e-13	9.106e-13	0.0002
16	50	Unbiased-50k	9.113e-13	9.118e-13	0.0005
17	60	Biased-50k	9.083e-13	9.09e-13	0.0007
18	60	Biased-50k	9.066e-13	9.084e-13	0.0018
19	60	Biased-50k	9.081e-13	9.086e-13	0.0005
20	60	Biased-50k	9.081e-13	9.081e-13	0
21	60	Biased-50k	9.077e-13	9.076e-13	-0.0001
24	100	Unbiased-100k	9.051e-13	9.049e-13	-0.0002
25	100	Unbiased-100k	9.103e-13	9.106e-13	0.0003
26	100	Unbiased-100k	9.084e-13	9.086e-13	0.0002
27	100	Unbiased-100k	9.081e-13	9.095e-13	0.0014
28	100	Unbiased-100k	9.109e-13	9.092e-13	-0.0017
29	110	Biased-100k	9.068e-13	9.089e-13	0.0021
30	110	Biased-100k	9.097e-13	9.101e-13	0.0004
31	110	Biased-100k	9.052e-13	9.068e-13	0.0016
32	110	Biased-100k	9.081e-13	9.083e-13	0.0002
34	110	Biased-100k	9.067e-13	9.081e-13	0.0014

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.041e-13	9.074e-13	9.109e-13	3.4044e-15	9.04e-13	9.077e-13	9.115e-13	3.751e-15	-0.0001	0.0003	0.0006	0.00036056
50	9.056e-13	9.0894e-13	9.113e-13	2.4876e-15	9.059e-13	9.0912e-13	9.118e-13	2.4407e-15	-0.0004	0.00018	0.0005	0.00034205
60	9.066e-13	9.0776e-13	9.083e-13	6.8411e-16	9.076e-13	9.0834e-13	9.09e-13	5.2726e-16	-0.0001	0.00058	0.0018	0.00075961
100	9.051e-13	9.0856e-13	9.109e-13	2.2755e-15	9.049e-13	9.0856e-13	9.106e-13	2.1709e-15	-0.0017	-2.2204e-17	0.0014	0.0011203
110	9.052e-13	9.073e-13	9.097e-13	1.6897e-15	9.068e-13	9.0844e-13	9.101e-13	1.2033e-15	0.0002	0.00114	0.0021	0.00081117

Test: 31.8 VSENSE_VTH_FALLING_FAULT(PWRGD|FallingFault/PWRGD4/7/7///90.9/634//1.8///@VSENSE_VTH_FALLING





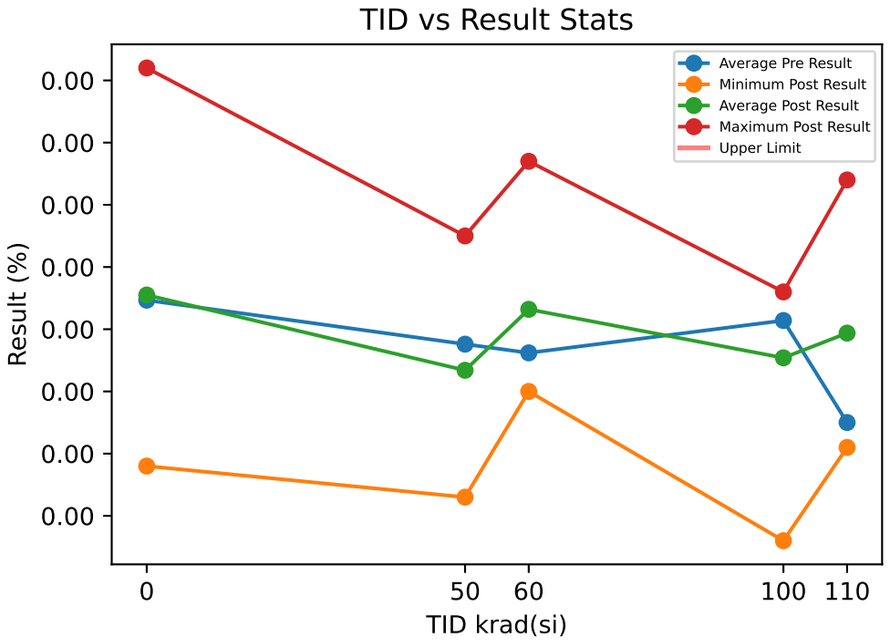
Test Results (No Limits Specified (%))

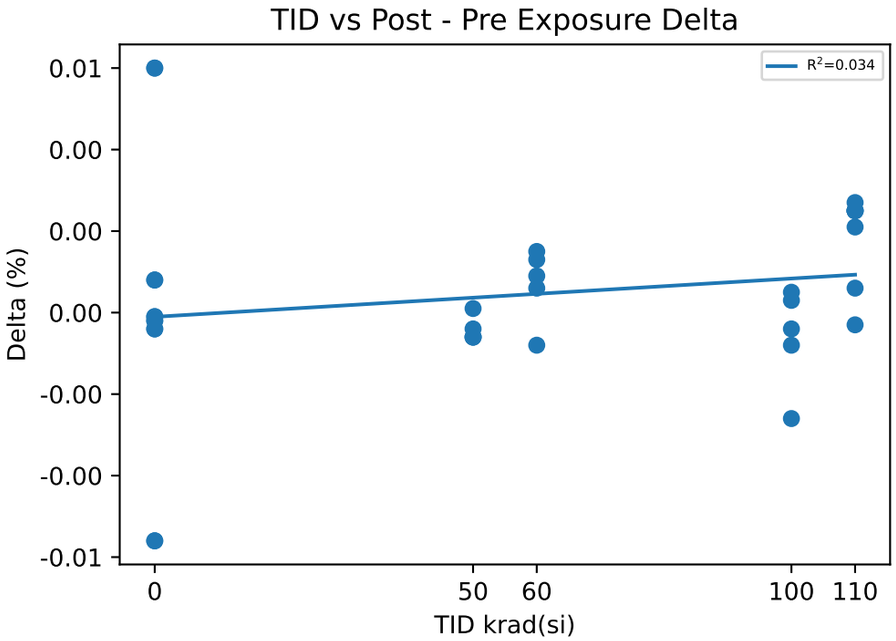
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.111e-13	9.109e-13	-0.0002
2	0	CU2	9.085e-13	9.084e-13	-0.0001
3	0	CU3	9.105e-13	9.101e-13	-0.0004
11	50	Unbiased-50k	9.068e-13	9.061e-13	-0.0007
12	50	Unbiased-50k	9.08e-13	9.092e-13	0.0012
13	50	Unbiased-50k	9.096e-13	9.098e-13	0.0002
14	50	Unbiased-50k	9.061e-13	9.062e-13	0.0001
16	50	Unbiased-50k	9.09e-13	9.094e-13	0.0004
17	60	Biased-50k	9.083e-13	9.083e-13	0
18	60	Biased-50k	9.076e-13	9.095e-13	0.0019
19	60	Biased-50k	9.062e-13	9.066e-13	0.0004
20	60	Biased-50k	9.093e-13	9.111e-13	0.0018
21	60	Biased-50k	9.074e-13	9.089e-13	0.0015
24	100	Unbiased-100k	9.071e-13	9.069e-13	-0.0002
25	100	Unbiased-100k	9.083e-13	9.077e-13	-0.0006
26	100	Unbiased-100k	9.093e-13	9.088e-13	-0.0005
27	100	Unbiased-100k	9.09e-13	9.103e-13	0.0013
28	100	Unbiased-100k	9.089e-13	9.09e-13	0.0001
29	110	Biased-100k	9.074e-13	9.085e-13	0.0011
30	110	Biased-100k	9.07e-13	9.081e-13	0.0011
31	110	Biased-100k	9.067e-13	9.075e-13	0.0008
32	110	Biased-100k	9.073e-13	9.097e-13	0.0024
34	110	Biased-100k	9.1e-13	9.122e-13	0.0022

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.085e-13	9.1003e-13	9.111e-13	1.3614e-15	9.084e-13	9.098e-13	9.109e-13	1.2767e-15	-0.0004	-0.00023333	-0.0001	0.00015275
50	9.061e-13	9.079e-13	9.096e-13	1.4629e-15	9.061e-13	9.0814e-13	9.098e-13	1.8298e-15	-0.0007	0.00024	0.0012	0.00068044
60	9.062e-13	9.0776e-13	9.093e-13	1.1459e-15	9.066e-13	9.0888e-13	9.111e-13	1.6468e-15	0	0.00112	0.0019	0.00086429
100	9.071e-13	9.0852e-13	9.093e-13	8.7293e-16	9.069e-13	9.0854e-13	9.103e-13	1.3012e-15	-0.0006	2e-05	0.0013	0.00076616
110	9.067e-13	9.0768e-13	9.1e-13	1.3255e-15	9.075e-13	9.092e-13	9.122e-13	1.8601e-15	0.0008	0.00152	0.0024	0.00072595

Test: 31.9 VSENSE_VTH_RISING_GOOD(PWRGD|RisingGood/PWRGD1/7/7///90.9/634//1.8///@VSENSE_VTH_RISING_





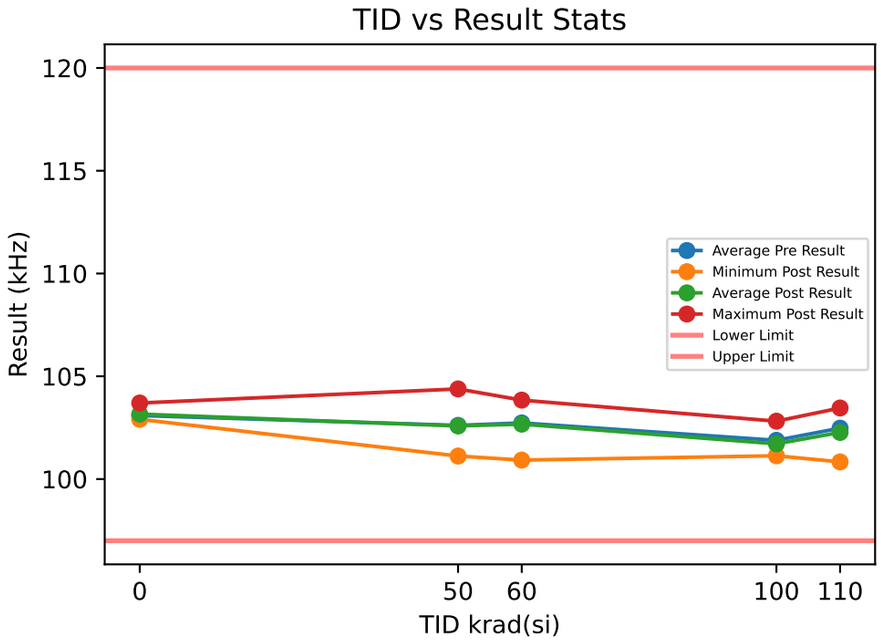
Test Results (No Limits Specified (%))

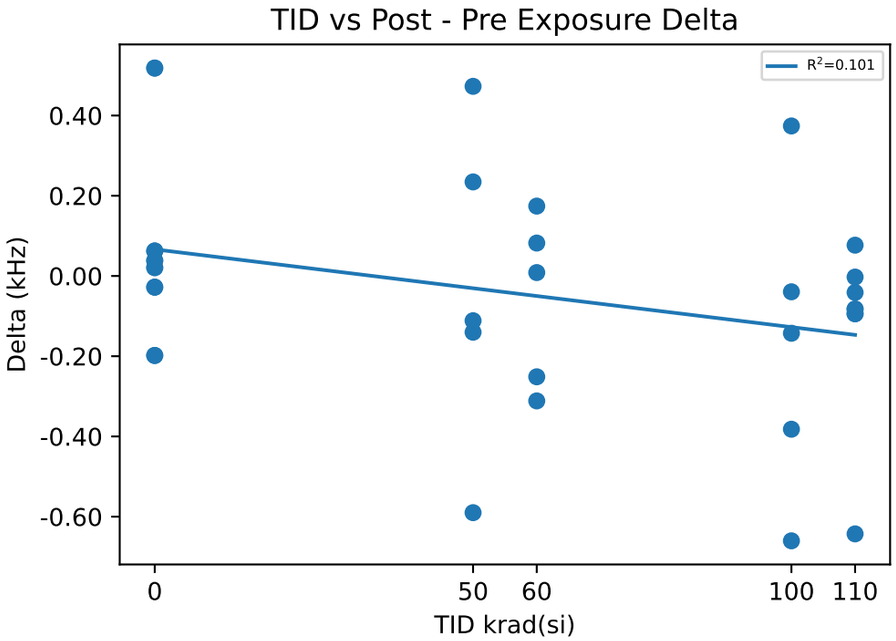
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	9.389e-13	9.387e-13	-0.0002
2	0	CU2	9.443e-13	9.442e-13	-0.0001
3	0	CU3	9.382e-13	9.378e-13	-0.0004
11	50	Unbiased-50k	9.414e-13	9.415e-13	0.0001
12	50	Unbiased-50k	9.379e-13	9.373e-13	-0.0006
13	50	Unbiased-50k	9.407e-13	9.401e-13	-0.0006
14	50	Unbiased-50k	9.394e-13	9.388e-13	-0.0006
16	50	Unbiased-50k	9.394e-13	9.39e-13	-0.0004
17	60	Biased-50k	9.395e-13	9.404e-13	0.0009
18	60	Biased-50k	9.385e-13	9.398e-13	0.0013
19	60	Biased-50k	9.391e-13	9.397e-13	0.0006
20	60	Biased-50k	9.398e-13	9.39e-13	-0.0008
21	60	Biased-50k	9.412e-13	9.427e-13	0.0015
24	100	Unbiased-100k	9.392e-13	9.366e-13	-0.0026
25	100	Unbiased-100k	9.406e-13	9.402e-13	-0.0004
26	100	Unbiased-100k	9.4e-13	9.403e-13	0.0003
27	100	Unbiased-100k	9.395e-13	9.4e-13	0.0005
28	100	Unbiased-100k	9.414e-13	9.406e-13	-0.0008
29	110	Biased-100k	9.38e-13	9.386e-13	0.0006
30	110	Biased-100k	9.427e-13	9.424e-13	-0.0003
31	110	Biased-100k	9.385e-13	9.412e-13	0.0027
32	110	Biased-100k	9.36e-13	9.381e-13	0.0021
34	110	Biased-100k	9.373e-13	9.398e-13	0.0025

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.382e-13	9.4047e-13	9.443e-13	3.3382e-15	9.378e-13	9.4023e-13	9.442e-13	3.4646e-15	-0.0004	-0.00023333	-0.0001	0.00015275
50	9.379e-13	9.3976e-13	9.414e-13	1.3502e-15	9.373e-13	9.3934e-13	9.415e-13	1.5662e-15	-0.0006	-0.00042	0.0001	0.00030332
60	9.385e-13	9.3962e-13	9.412e-13	1.0085e-15	9.39e-13	9.4032e-13	9.427e-13	1.4202e-15	-0.0008	0.0007	0.0015	0.0009083
100	9.392e-13	9.4014e-13	9.414e-13	8.8204e-16	9.366e-13	9.3954e-13	9.406e-13	1.6577e-15	-0.0026	-0.0006	0.0005	0.0012349
110	9.36e-13	9.385e-13	9.427e-13	2.5288e-15	9.381e-13	9.4002e-13	9.424e-13	1.7894e-15	-0.0003	0.00152	0.0027	0.0013084

Device Test: 32.2 EXT_SET_FREQ_100KHZ(IntFreq|Freq/RT_511/3/3///90.9/634//1.8///@EXT_SET_FREQ_100KHZ)





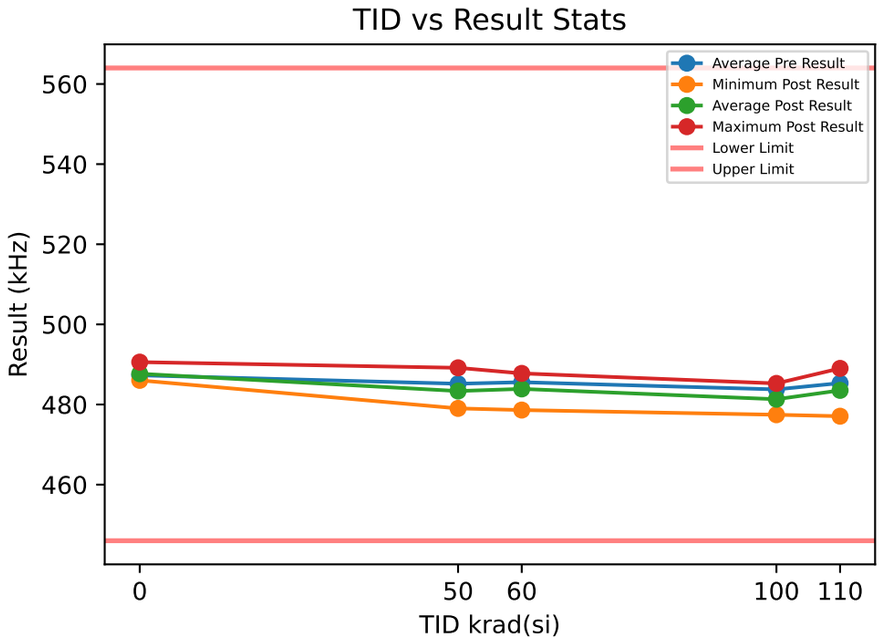
Test Results (Lower Limit = 97.0, Upper Limit = 120.0 (kHz))

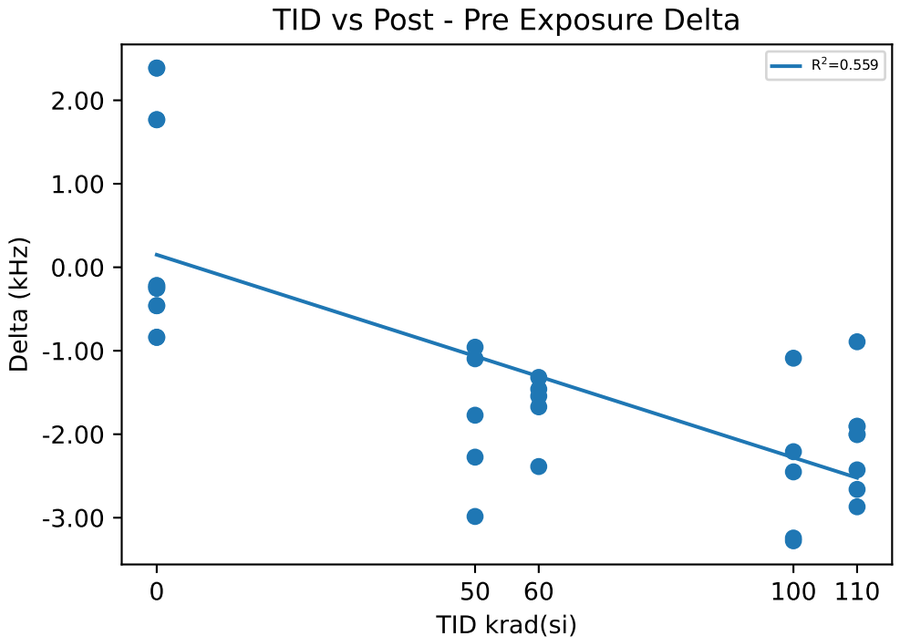
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.18	103.2	0.0209
2	0	CU2	102.99	103.05	0.0623
3	0	CU3	103.11	103.08	-0.0279
11	50	Unbiased-50k	101.71	101.12	-0.59
12	50	Unbiased-50k	102.41	102.27	-0.1402
13	50	Unbiased-50k	102.46	102.69	0.2345
14	50	Unbiased-50k	101.98	102.45	0.4728
16	50	Unbiased-50k	104.5	104.38	-0.1115
17	60	Biased-50k	101	101.09	0.0821
18	60	Biased-50k	103.63	103.8	0.1742
19	60	Biased-50k	101.23	100.92	-0.3114
20	60	Biased-50k	103.83	103.84	0.0085
21	60	Biased-50k	103.96	103.71	-0.2513
24	100	Unbiased-100k	101.48	101.33	-0.1428
25	100	Unbiased-100k	101.51	101.13	-0.382
26	100	Unbiased-100k	101.9	101.86	-0.0394
27	100	Unbiased-100k	101.06	101.43	0.374
28	100	Unbiased-100k	103.48	102.82	-0.6602
29	110	Biased-100k	100.84	100.84	-0.0027
30	110	Biased-100k	104.1	103.46	-0.6429
31	110	Biased-100k	103.13	103.2	0.0768
32	110	Biased-100k	102.08	102.04	-0.0411
34	110	Biased-100k	102.24	102.16	-0.0824

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	102.99	103.09	103.18	0.097216	103.05	103.11	103.2	0.080927	-0.0279	0.018433	0.0623	0.045151
50	101.71	102.61	104.5	1.0982	101.12	102.58	104.38	1.1739	-0.59	-0.02688	0.4728	0.40469
60	101	102.73	103.96	1.4786	100.92	102.67	103.84	1.5239	-0.3114	-0.05958	0.1742	0.21186
100	101.06	101.88	103.48	0.93851	101.13	101.71	102.82	0.67064	-0.6602	-0.17008	0.374	0.38697
110	100.84	102.48	104.1	1.2199	100.84	102.34	103.46	1.0462	-0.6429	-0.13846	0.0768	0.28803

Device Test: 32.3 EXT_SET_FREQ_500KHZ(IntFreq|Freq/RT_90P9/3/3///90.9/634//1.8///@EXT_SET_FREQ_500KHZ)





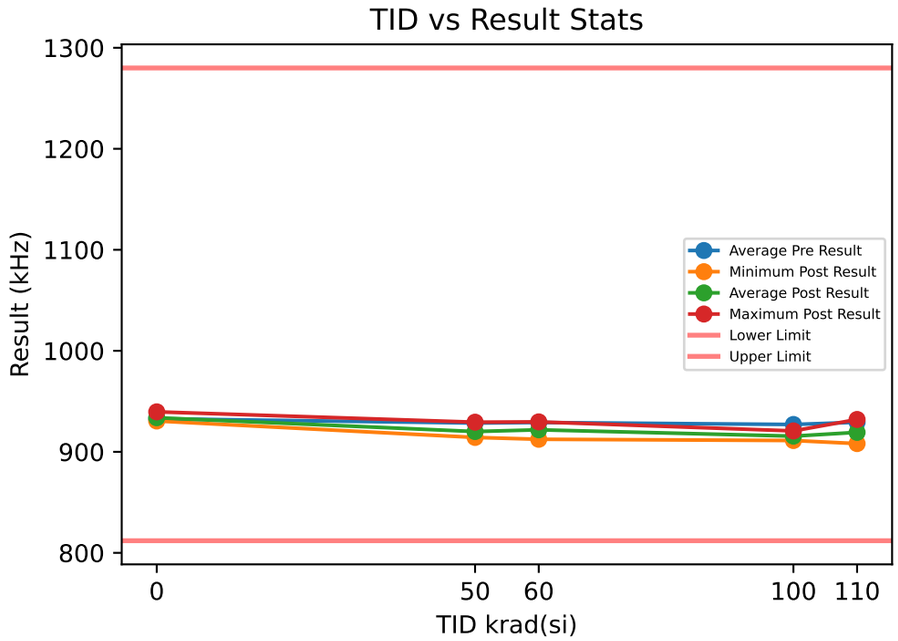
Test Results (Lower Limit = 446.0, Upper Limit = 564.0 (kHz))

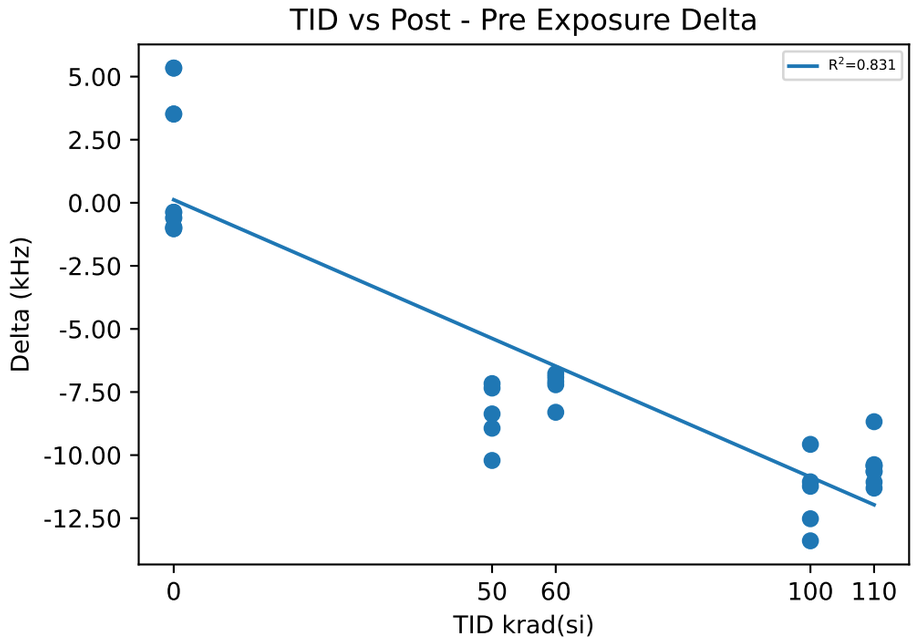
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	488.19	487.94	-0.2504
2	0	CU2	486.49	486.03	-0.4603
3	0	CU3	487.17	486.95	-0.22
11	50	Unbiased-50k	482.01	479.03	-2.9853
12	50	Unbiased-50k	483.78	482.01	-1.7723
13	50	Unbiased-50k	484.49	483.4	-1.0962
14	50	Unbiased-50k	484.19	483.23	-0.9575
16	50	Unbiased-50k	491.43	489.16	-2.2745
17	60	Biased-50k	483.16	481.49	-1.6719
18	60	Biased-50k	487.28	485.96	-1.3195
19	60	Biased-50k	481	478.61	-2.387
20	60	Biased-50k	487.09	485.63	-1.46
21	60	Biased-50k	489.31	487.76	-1.5438
24	100	Unbiased-100k	484.44	482.23	-2.2092
25	100	Unbiased-100k	480.72	477.44	-3.2769
26	100	Unbiased-100k	483.58	481.13	-2.4509
27	100	Unbiased-100k	481.59	480.5	-1.0892
28	100	Unbiased-100k	488.51	485.26	-3.2438
29	110	Biased-100k	479.5	477.08	-2.4273
30	110	Biased-100k	491.88	489.02	-2.8692
31	110	Biased-100k	486.12	485.23	-0.8924
32	110	Biased-100k	483.12	480.46	-2.6609
34	110	Biased-100k	486.07	484.16	-1.9054

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	486.49	487.29	488.19	0.85789	486.03	486.98	487.94	0.95741	-0.4603	-0.31023	-0.22	0.13085
50	482.01	485.18	491.43	3.6247	479.03	483.37	489.16	3.6831	-2.9853	-1.8172	-0.9575	0.8418
60	481	485.57	489.31	3.3863	478.61	483.89	487.76	3.7386	-2.387	-1.6764	-1.3195	0.41736
100	480.72	483.77	488.51	3.041	477.44	481.31	485.26	2.8336	-3.2769	-2.454	-1.0892	0.89771
110	479.5	485.34	491.88	4.5536	477.08	483.19	489.02	4.5783	-2.8692	-2.151	-0.8924	0.79002

Device Test: 32.4 EXT_SET_FREQ_1000KHZ(IntFreq|Freq/RT37P4/3/3///90.9/634//1.8///@EXT_SET_FREQ_1000KHZ)





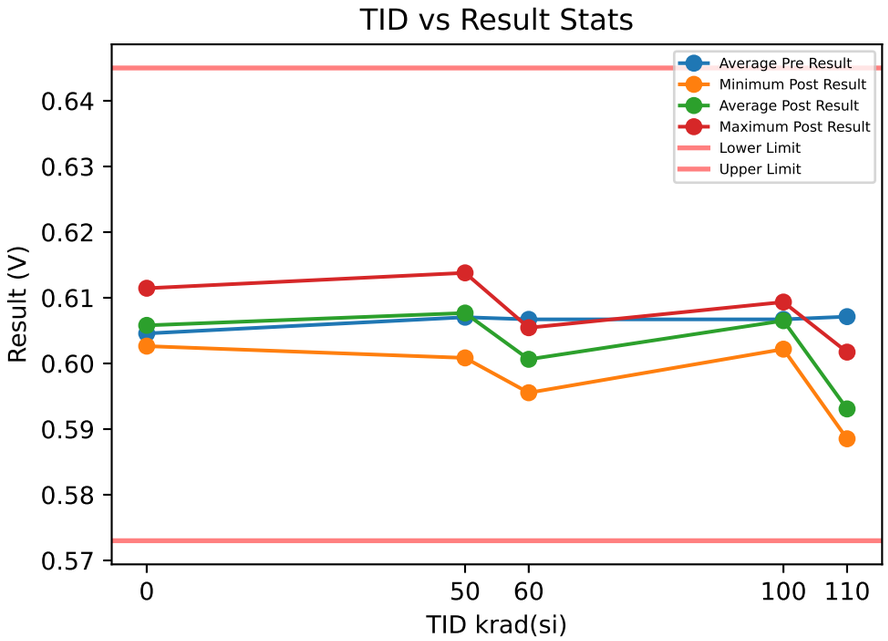
Test Results (Lower Limit = 812.0, Upper Limit = 1280.0 (kHz))

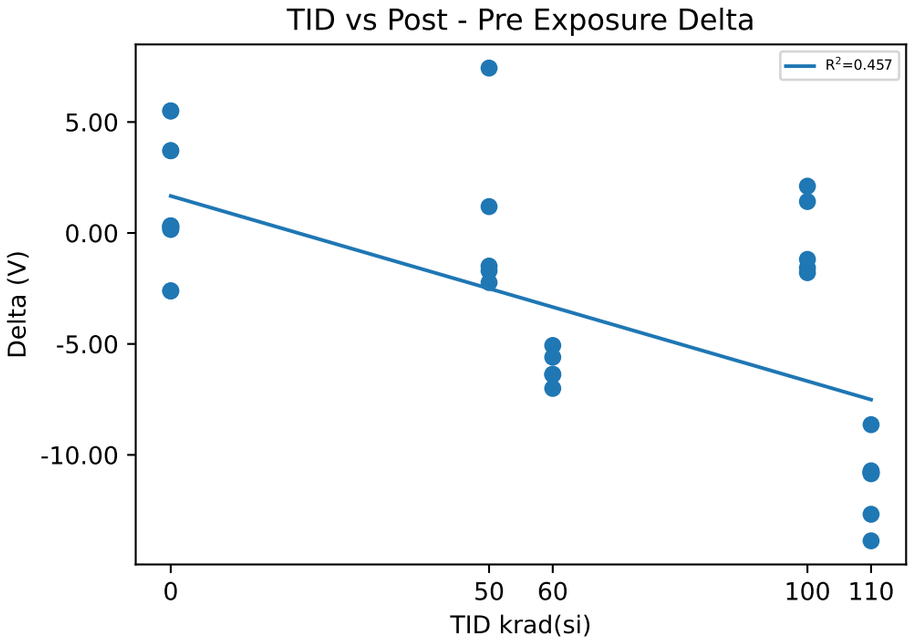
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	934.24	933.87	-0.3756
2	0	CU2	931.54	930.51	-1.0263
3	0	CU3	932.52	931.92	-0.5986
11	50	Unbiased-50k	924.46	914.25	-10.213
12	50	Unbiased-50k	926.2	917.83	-8.3673
13	50	Unbiased-50k	927.55	920.21	-7.3421
14	50	Unbiased-50k	925.99	918.82	-7.1654
16	50	Unbiased-50k	938.28	929.35	-8.9344
17	60	Biased-50k	927.66	920.75	-6.9153
18	60	Biased-50k	931	924.23	-6.7721
19	60	Biased-50k	920.73	912.43	-8.3028
20	60	Biased-50k	929	921.91	-7.0847
21	60	Biased-50k	936.86	929.65	-7.2116
24	100	Unbiased-100k	928.3	917.24	-11.059
25	100	Unbiased-100k	923.71	911.19	-12.522
26	100	Unbiased-100k	926.83	915.6	-11.237
27	100	Unbiased-100k	922.47	912.89	-9.5742
28	100	Unbiased-100k	934.09	920.69	-13.397
29	110	Biased-100k	919.22	908.15	-11.069
30	110	Biased-100k	942.41	932.03	-10.378
31	110	Biased-100k	930.25	921.57	-8.6759
32	110	Biased-100k	923.95	912.64	-11.309
34	110	Biased-100k	930.5	920.06	-10.433

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	931.54	932.77	934.24	1.3693	930.51	932.1	933.87	1.6851	-1.0263	-0.66683	-0.3756	0.33067
50	924.46	928.5	938.28	5.5795	914.25	920.09	929.35	5.6251	-10.213	-8.4044	-7.1654	1.2465
60	920.73	929.05	936.86	5.8292	912.43	921.79	929.65	6.2535	-8.3028	-7.2573	-6.7721	0.60773
100	922.47	927.08	934.09	4.5644	911.19	915.52	920.69	3.7217	-13.397	-11.558	-9.5742	1.466
110	919.22	929.26	942.41	8.7231	908.15	918.89	932.03	9.1596	-11.309	-10.373	-8.6759	1.0301

Device Test: 33.1 EN_VTH_RISING(Enable|RisingThreshold/EN1/3/3///90.9/634//0///@EN_VTH_RISING)





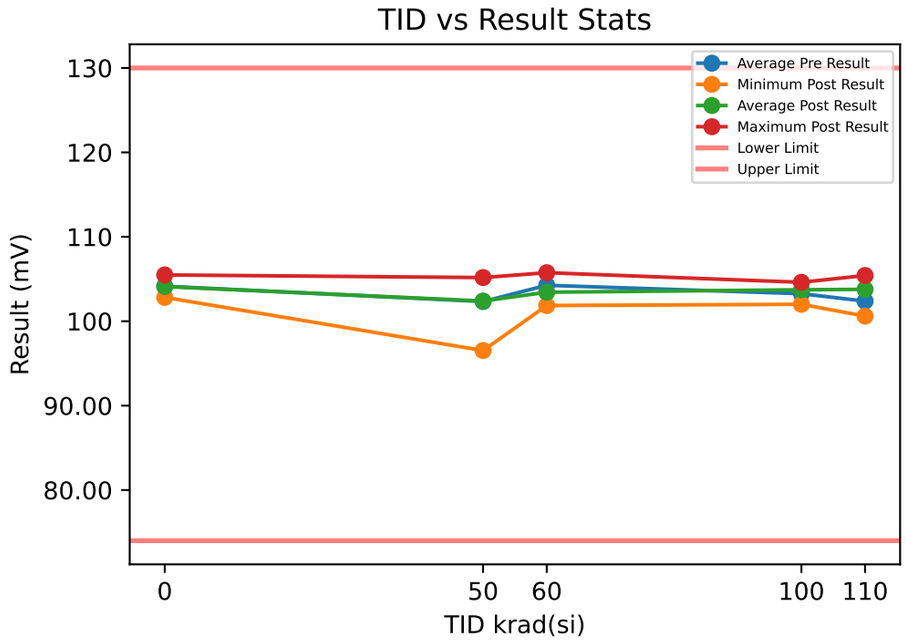
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

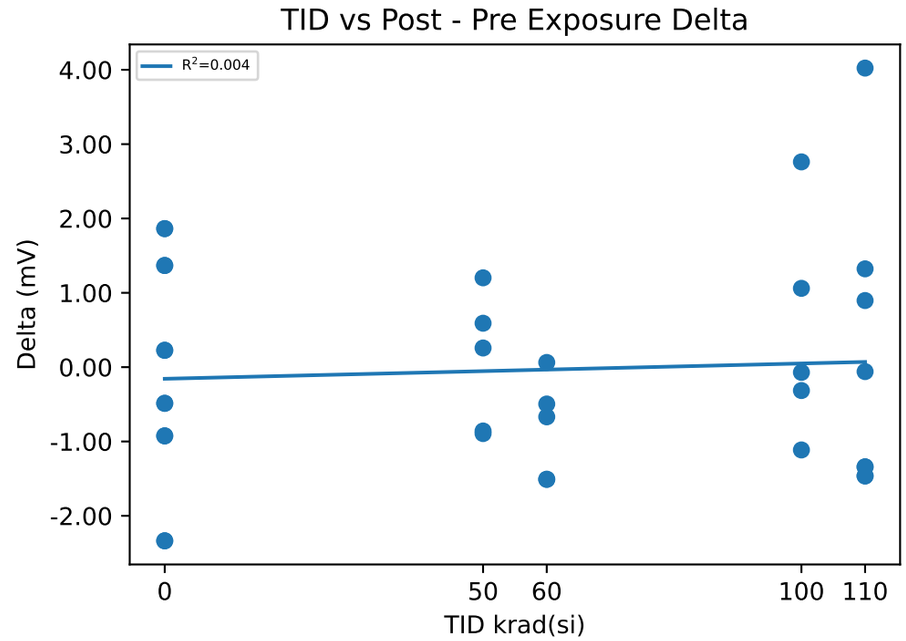
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.60595	0.60624	0.2861
2	0	CU2	0.60251	0.60268	0.1662
3	0	CU3	0.60525	0.60556	0.3194
11	50	Unbiased-50k	0.60699	0.60549	-1.4917
12	50	Unbiased-50k	0.60636	0.6138	7.4314
13	50	Unbiased-50k	0.61056	0.60833	-2.2324
14	50	Unbiased-50k	0.59965	0.60084	1.1895
16	50	Unbiased-50k	0.61163	0.60992	-1.7046
17	60	Biased-50k	0.61051	0.60544	-5.0691
18	60	Biased-50k	0.60937	0.60301	-6.365
19	60	Biased-50k	0.60254	0.59554	-7.0031
20	60	Biased-50k	0.60707	0.60069	-6.3823
21	60	Biased-50k	0.60407	0.59847	-5.5965
24	100	Unbiased-100k	0.61081	0.60924	-1.5704
25	100	Unbiased-100k	0.60724	0.60935	2.1103
26	100	Unbiased-100k	0.60423	0.60565	1.4177
27	100	Unbiased-100k	0.60337	0.60218	-1.1897
28	100	Unbiased-100k	0.60792	0.60613	-1.7886
29	110	Biased-100k	0.60537	0.5915	-13.872
30	110	Biased-100k	0.61036	0.60172	-8.6375
31	110	Biased-100k	0.61205	0.60133	-10.718
32	110	Biased-100k	0.60848	0.59581	-12.675
34	110	Biased-100k	0.59937	0.58852	-10.843

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60251	0.60457	0.60595	0.0018176	0.60268	0.60483	0.60624	0.001892	0.1662	0.25723	0.3194	0.080576
50	0.59965	0.60704	0.61163	0.0047021	0.60084	0.60768	0.6138	0.004857	-2.2324	0.63844	7.4314	4.0223
60	0.60254	0.60671	0.61051	0.0033911	0.59554	0.60063	0.60544	0.0038525	-7.0031	-6.0832	-5.0691	0.75504
100	0.60337	0.60671	0.61081	0.0029953	0.60218	0.60651	0.60935	0.0029658	-1.7886	-0.20414	2.1103	1.8259
110	0.59937	0.60713	0.61205	0.0049955	0.58852	0.59578	0.60172	0.0058543	-13.872	-11.349	-8.6375	2.0081

Device Test: 33.10 EN_VTH_HYST(Enable|Hys/EN2/3/3///90.9/634//0///@EN_VTH_HYST)





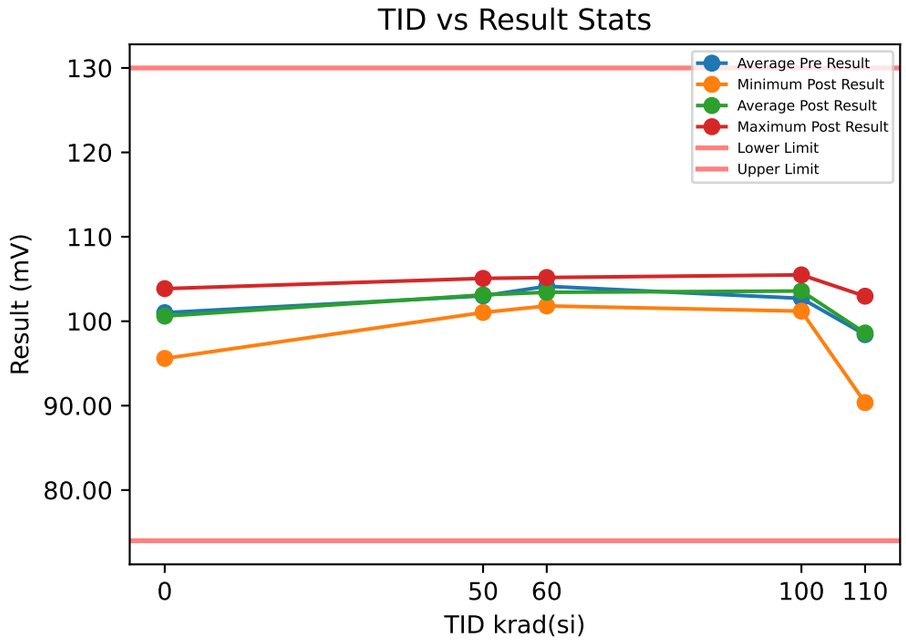
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

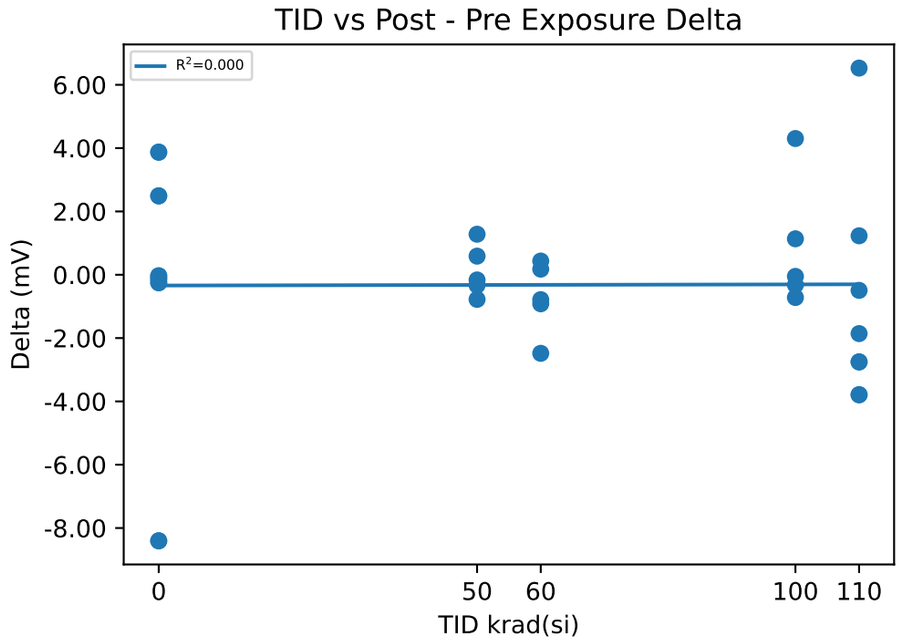
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.31	102.83	-0.4867
2	0	CU2	105.26	105.49	0.2266
3	0	CU3	103.89	102.96	-0.9246
11	50	Unbiased-50k	103.28	102.39	-0.8936
12	50	Unbiased-50k	97.388	96.529	-0.8589
13	50	Unbiased-50k	101.67	102.87	1.2017
14	50	Unbiased-50k	104.41	105	0.5908
16	50	Unbiased-50k	104.91	105.17	0.2577
17	60	Biased-50k	103.37	101.86	-1.5081
18	60	Biased-50k	104.93	104.44	-0.4958
19	60	Biased-50k	106.42	105.75	-0.6685
20	60	Biased-50k	103.16	103.22	0.0629
21	60	Biased-50k	103.41	101.9	-1.5092
24	100	Unbiased-100k	103.25	104.31	1.0601
25	100	Unbiased-100k	102.08	102.01	-0.0703
26	100	Unbiased-100k	105.73	104.61	-1.1139
27	100	Unbiased-100k	104.67	104.36	-0.3148
28	100	Unbiased-100k	100.59	103.35	2.7614
29	110	Biased-100k	105.01	104.95	-0.0599
30	110	Biased-100k	100.31	101.2	0.8961
31	110	Biased-100k	99.282	100.6	1.3225
32	110	Biased-100k	101.39	105.42	4.0233
34	110	Biased-100k	105.92	104.45	-1.4634

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	103.31	104.15	105.26	0.99994	102.83	103.76	105.49	1.498	-0.9246	-0.3949	0.2266	0.58106
50	97.388	102.33	104.91	3.0329	96.529	102.39	105.17	3.5055	-0.8936	0.05954	1.2017	0.91897
60	103.16	104.26	106.42	1.3997	101.86	103.43	105.75	1.6763	-1.5092	-0.82374	0.0629	0.68117
100	100.59	103.26	105.73	2.0383	102.01	103.73	104.61	1.0743	-1.1139	0.4645	2.7614	1.5013
110	99.282	102.38	105.92	2.9275	100.6	103.32	105.42	2.247	-1.4634	0.94372	4.0233	2.0268

Device Test: 33.11 EN_VTH_HYST(Enable|Hys/EN3/3/3///90.9/634//0///@EN_VTH_HYST)





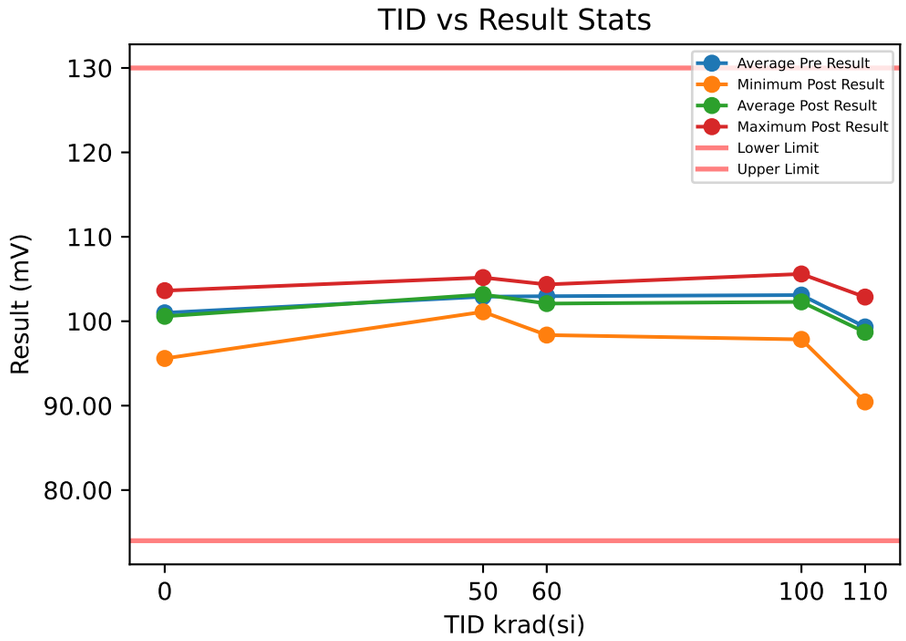
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

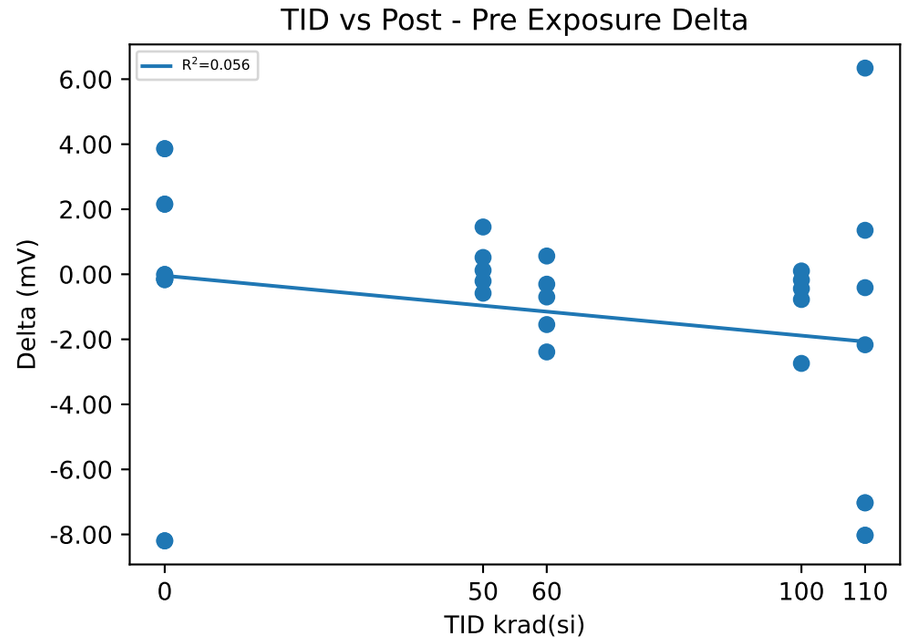
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	104	103.74	-0.2513
2	0	CU2	101.37	101.24	-0.1327
3	0	CU3	97.683	97.649	-0.0346
11	50	Unbiased-50k	102.07	103.36	1.2803
12	50	Unbiased-50k	102.42	101.65	-0.7771
13	50	Unbiased-50k	105.24	105.07	-0.1639
14	50	Unbiased-50k	101.37	101.04	-0.3295
16	50	Unbiased-50k	103.91	104.49	0.5881
17	60	Biased-50k	104.26	103.34	-0.9165
18	60	Biased-50k	101.41	101.84	0.4335
19	60	Biased-50k	105.97	105.18	-0.786
20	60	Biased-50k	104.78	104.96	0.1777
21	60	Biased-50k	104.3	101.81	-2.4819
24	100	Unbiased-100k	101.91	101.19	-0.7188
25	100	Unbiased-100k	104.35	105.49	1.1356
26	100	Unbiased-100k	103.17	102.85	-0.3184
27	100	Unbiased-100k	103.56	103.5	-0.0515
28	100	Unbiased-100k	100.55	104.86	4.3033
29	110	Biased-100k	102.01	100.15	-1.8585
30	110	Biased-100k	90.847	90.353	-0.4931
31	110	Biased-100k	101.26	102.49	1.231
32	110	Biased-100k	96.436	102.96	6.5285
34	110	Biased-100k	101.49	97.704	-3.7895

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.683	101.02	104	3.1706	97.649	100.88	103.74	3.0633	-0.2513	-0.13953	-0.0346	0.10851
50	101.37	103	105.24	1.5563	101.04	103.12	105.07	1.7517	-0.7771	0.11958	1.2803	0.81438
60	101.41	104.14	105.97	1.6751	101.81	103.43	105.18	1.6216	-2.4819	-0.71464	0.4335	1.1493
100	100.55	102.71	104.35	1.4926	101.19	103.58	105.49	1.6969	-0.7188	0.87004	4.3033	2.0398
110	90.847	98.41	102.01	4.7885	90.353	98.734	102.96	5.1318	-3.7895	0.32368	6.5285	3.9265

Device Test: 33.12 EN_VTH_HYST(Enable|Hys/EN4/3/3///90.9/634//0///@EN_VTH_HYST)





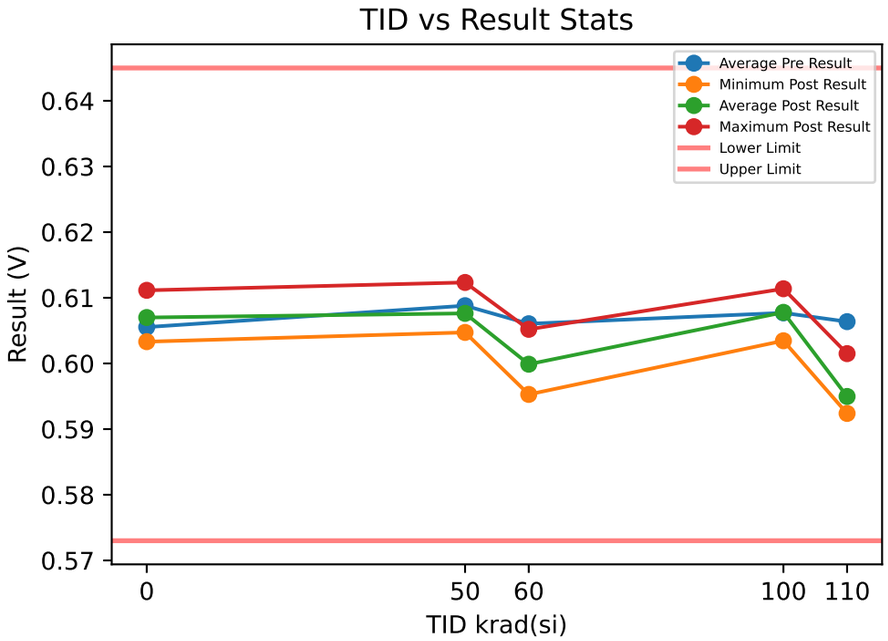
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

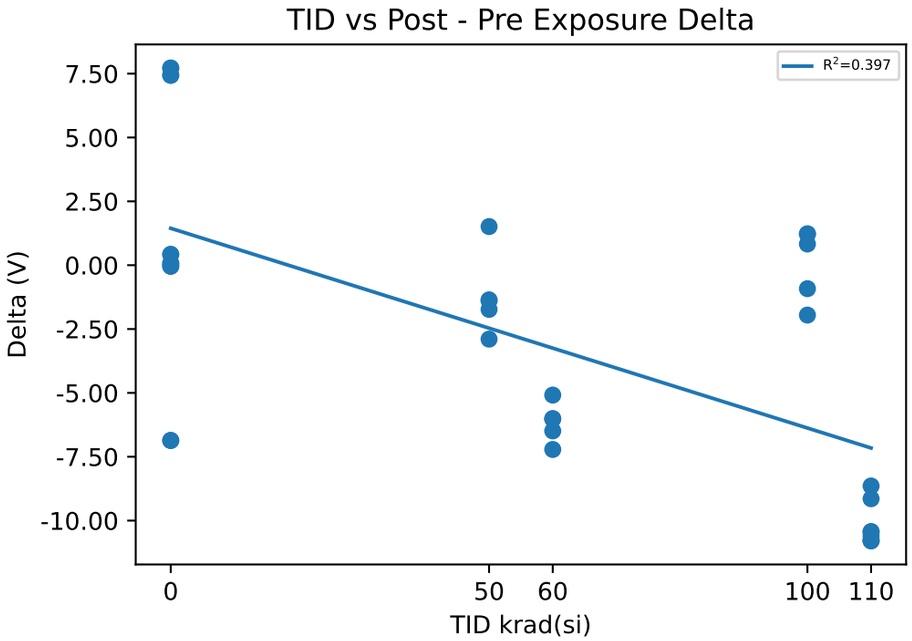
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.79	103.62	-0.1643
2	0	CU2	101.47	101.46	-0.0077
3	0	CU3	97.742	97.602	-0.1399
11	50	Unbiased-50k	101.92	103.38	1.4543
12	50	Unbiased-50k	102.39	101.81	-0.5818
13	50	Unbiased-50k	105.05	105.17	0.1226
14	50	Unbiased-50k	101.33	101.12	-0.2108
16	50	Unbiased-50k	103.85	104.36	0.517
17	60	Biased-50k	104.35	103.65	-0.6978
18	60	Biased-50k	101.51	102.08	0.5618
19	60	Biased-50k	99.909	98.362	-1.5464
20	60	Biased-50k	104.66	104.36	-0.3046
21	60	Biased-50k	104.4	102.01	-2.3884
24	100	Unbiased-100k	102.15	101.37	-0.7752
25	100	Unbiased-100k	106.04	105.6	-0.4428
26	100	Unbiased-100k	103.18	103.01	-0.1754
27	100	Unbiased-100k	103.54	103.65	0.1018
28	100	Unbiased-100k	100.59	97.847	-2.7407
29	110	Biased-100k	102.11	99.94	-2.1678
30	110	Biased-100k	90.851	90.439	-0.4117
31	110	Biased-100k	101.16	102.51	1.3522
32	110	Biased-100k	96.524	102.86	6.3412
34	110	Biased-100k	105.98	97.949	-8.0268

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.742	101	103.79	3.0493	97.602	100.89	103.62	3.0494	-0.1643	-0.10397	-0.0077	0.084257
50	101.33	102.91	105.05	1.5168	101.12	103.17	105.17	1.6994	-0.5818	0.26026	1.4543	0.78127
60	99.909	102.97	104.66	2.1382	98.362	102.09	104.36	2.3172	-2.3884	-0.87508	0.5618	1.136
100	100.59	103.1	106.04	2.0044	97.847	102.29	105.6	2.91	-2.7407	-0.80646	0.1018	1.1289
110	90.851	99.323	105.98	5.8093	90.439	98.741	102.86	5.0548	-8.0268	-0.58258	6.3412	5.2355

Device Test: 33.2 EN_VTH_RISING(Enable|RisingThreshold/EN2/3/3///90.9/634//0///@EN_VTH_RISING)





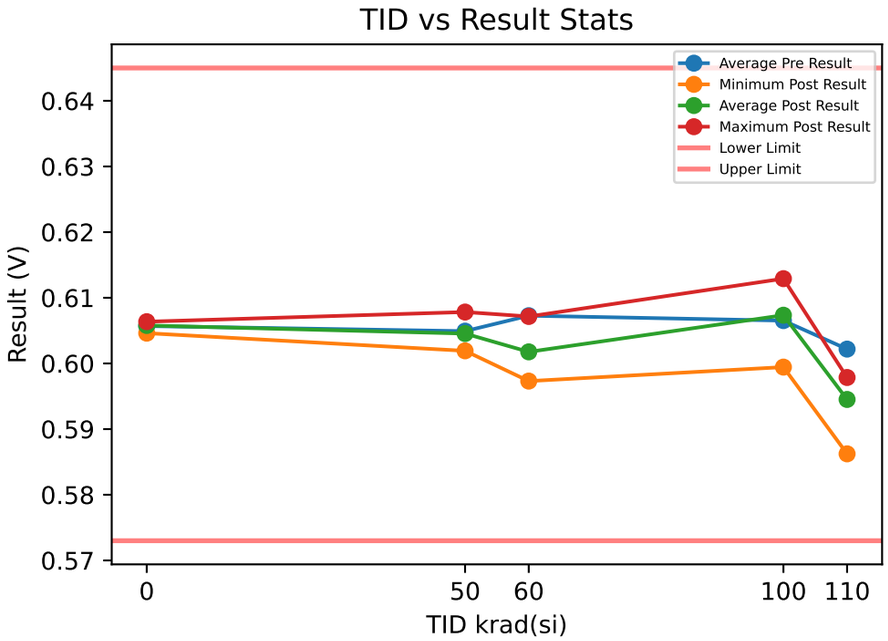
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

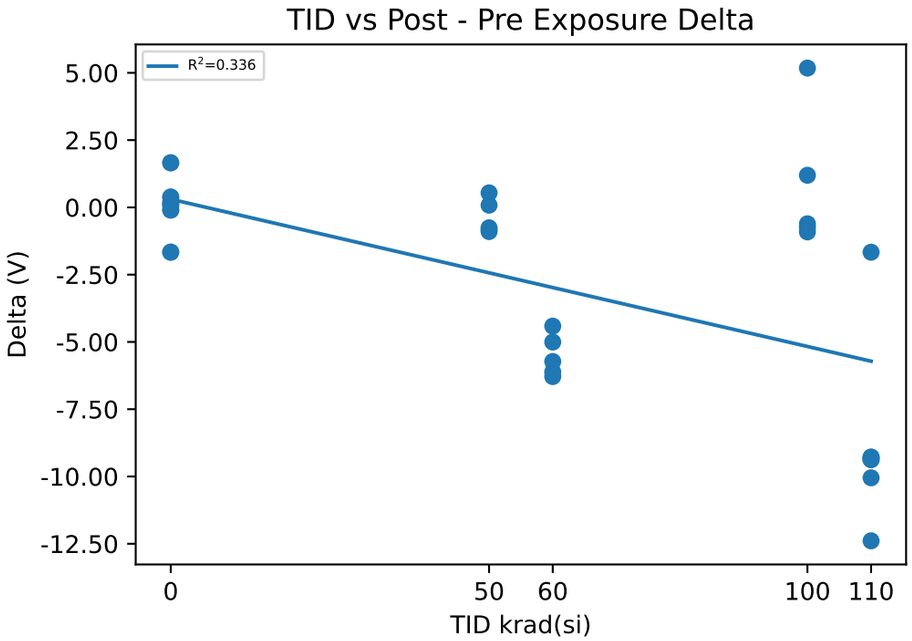
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.60342	0.60338	-0.0403
2	0	CU2	0.6103	0.61037	0.076
3	0	CU3	0.60289	0.60331	0.4217
11	50	Unbiased-50k	0.60738	0.60565	-1.7305
12	50	Unbiased-50k	0.60611	0.60472	-1.3915
13	50	Unbiased-50k	0.60675	0.60539	-1.3571
14	50	Unbiased-50k	0.6085	0.61002	1.5125
16	50	Unbiased-50k	0.61523	0.61233	-2.8947
17	60	Biased-50k	0.61028	0.6052	-5.0855
18	60	Biased-50k	0.6095	0.60301	-6.4878
19	60	Biased-50k	0.60499	0.59777	-7.2153
20	60	Biased-50k	0.60417	0.59815	-6.0224
21	60	Biased-50k	0.60129	0.59528	-6.0054
24	100	Unbiased-100k	0.6107	0.60875	-1.9529
25	100	Unbiased-100k	0.60388	0.6051	1.2254
26	100	Unbiased-100k	0.61229	0.61138	-0.9196
27	100	Unbiased-100k	0.609	0.61023	1.2241
28	100	Unbiased-100k	0.60262	0.60345	0.8295
29	110	Biased-100k	0.60375	0.59316	-10.596
30	110	Biased-100k	0.61014	0.60149	-8.6452
31	110	Biased-100k	0.60637	0.59723	-9.1438
32	110	Biased-100k	0.60838	0.59762	-10.765
34	110	Biased-100k	0.60318	0.59274	-10.434

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60289	0.60554	0.6103	0.0041326	0.60331	0.60569	0.61037	0.0040582	-0.0403	0.15247	0.4217	0.2403
50	0.60611	0.6088	0.61523	0.003702	0.60472	0.60762	0.61233	0.0033609	-2.8947	-1.1723	1.5125	1.6255
60	0.60129	0.60605	0.61028	0.0037798	0.59528	0.59988	0.6052	0.0040819	-7.2153	-6.1633	-5.0855	0.77757
100	0.60262	0.6077	0.61229	0.0042484	0.60345	0.60778	0.61138	0.0033814	-1.9529	0.0813	1.2254	1.4417
110	0.60318	0.60637	0.61014	0.0029709	0.59274	0.59645	0.60149	0.0036054	-10.765	-9.9166	-8.6452	0.95675

Device Test: 33.3 EN_VTH_RISING(Enable|RisingThreshold/EN3/3/3///90.9/634//0///@EN_VTH_RISING)





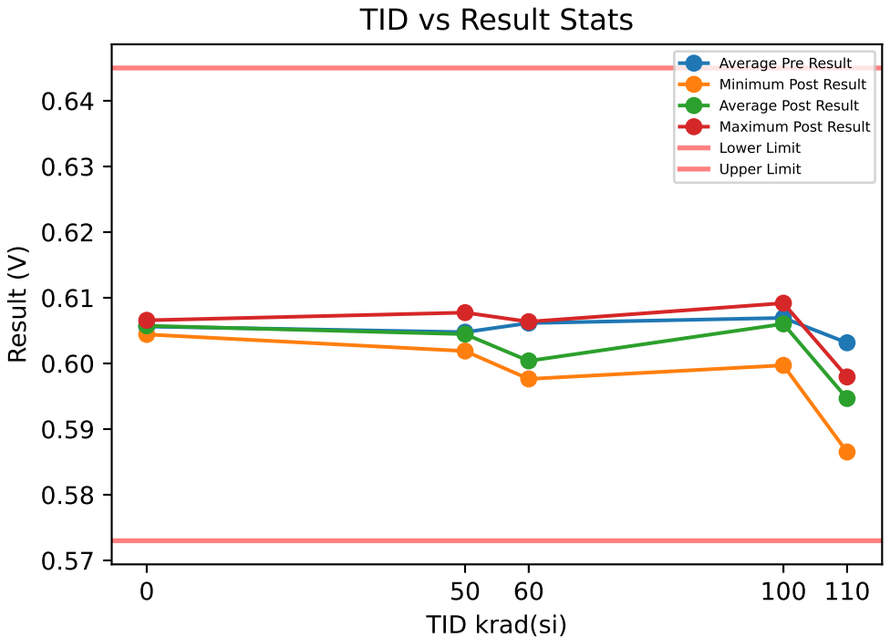
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

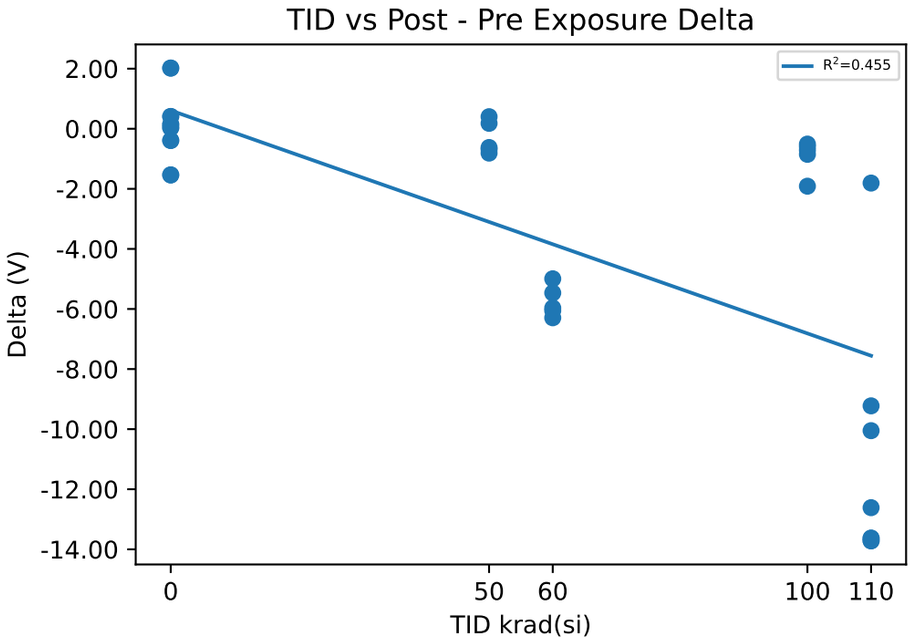
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.60628	0.60618	-0.0992
2	0	CU2	0.6061	0.60618	0.0796
3	0	CU3	0.6047	0.60509	0.3825
11	50	Unbiased-50k	0.60358	0.60268	-0.8982
12	50	Unbiased-50k	0.60268	0.60192	-0.7586
13	50	Unbiased-50k	0.60865	0.60783	-0.8218
14	50	Unbiased-50k	0.60755	0.60763	0.0827
16	50	Unbiased-50k	0.60215	0.60268	0.5395
17	60	Biased-50k	0.60373	0.598	-5.7279
18	60	Biased-50k	0.60343	0.59731	-6.115
19	60	Biased-50k	0.61038	0.60538	-5.0034
20	60	Biased-50k	0.61157	0.60715	-4.4122
21	60	Biased-50k	0.60726	0.60097	-6.287
24	100	Unbiased-100k	0.60005	0.59944	-0.6101
25	100	Unbiased-100k	0.60637	0.60756	1.1937
26	100	Unbiased-100k	0.60879	0.60788	-0.9113
27	100	Unbiased-100k	0.60968	0.60894	-0.7409
28	100	Unbiased-100k	0.60774	0.61291	5.177
29	110	Biased-100k	0.60591	0.59352	-12.391
30	110	Biased-100k	0.59556	0.58623	-9.3276
31	110	Biased-100k	0.60461	0.59457	-10.048
32	110	Biased-100k	0.59952	0.59786	-1.666
34	110	Biased-100k	0.60532	0.59603	-9.2822

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6047	0.60569	0.60628	0.00086224	0.60509	0.60581	0.60618	0.00063134	-0.0992	0.12097	0.3825	0.2435
50	0.60215	0.60492	0.60865	0.0029726	0.60192	0.60455	0.60783	0.0029213	-0.8982	-0.37128	0.5395	0.64542
60	0.60343	0.60727	0.61157	0.0037241	0.59731	0.60176	0.60715	0.0043803	-6.287	-5.5091	-4.4122	0.78725
100	0.60005	0.60652	0.60968	0.0038234	0.59944	0.60735	0.61291	0.0049077	-0.9113	0.82168	5.177	2.5789
110	0.59556	0.60218	0.60591	0.0044875	0.58623	0.59364	0.59786	0.0044518	-12.391	-8.543	-1.666	4.0474

Device Test: 33.4 EN_VTH_RISING(Enable|RisingThreshold/EN4/3/3///90.9/634//0///@EN_VTH_RISING)





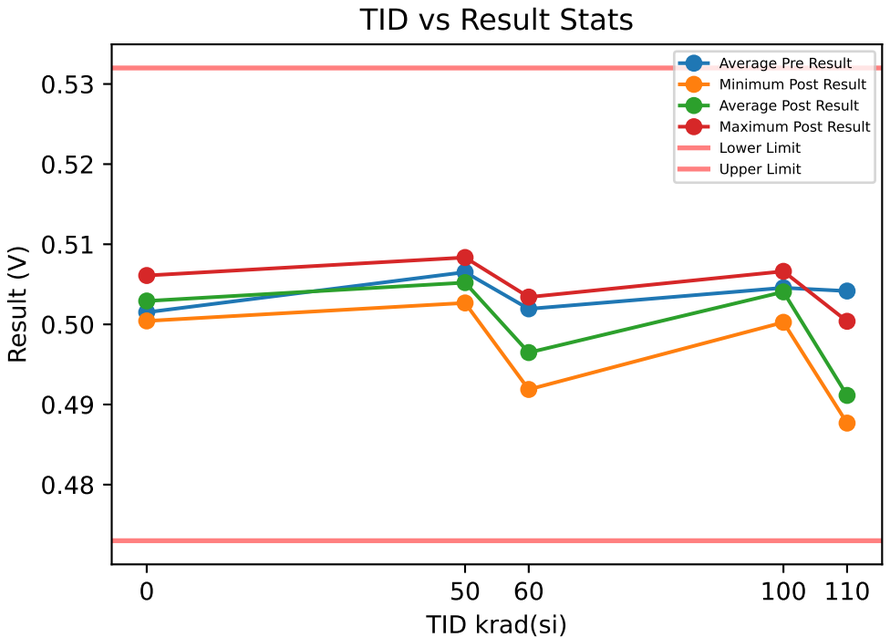
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

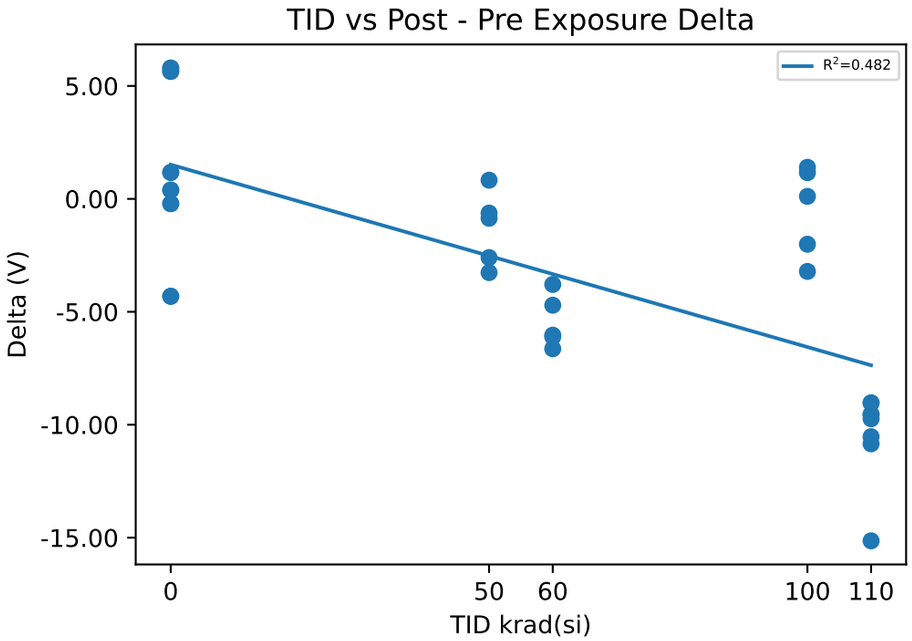
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.60595	0.60599	0.0336
2	0	CU2	0.60637	0.60651	0.144
3	0	CU3	0.60455	0.60496	0.4087
11	50	Unbiased-50k	0.60336	0.60255	-0.8108
12	50	Unbiased-50k	0.60251	0.60189	-0.6242
13	50	Unbiased-50k	0.60842	0.60774	-0.6854
14	50	Unbiased-50k	0.60737	0.60755	0.1799
16	50	Unbiased-50k	0.60217	0.60257	0.4017
17	60	Biased-50k	0.60386	0.5984	-5.4647
18	60	Biased-50k	0.60369	0.59764	-6.0546
19	60	Biased-50k	0.60428	0.59832	-5.9656
20	60	Biased-50k	0.61135	0.60636	-4.9944
21	60	Biased-50k	0.60753	0.60124	-6.2922
24	100	Unbiased-100k	0.60042	0.59971	-0.712
25	100	Unbiased-100k	0.60821	0.6077	-0.5102
26	100	Unbiased-100k	0.60868	0.60783	-0.8518
27	100	Unbiased-100k	0.60977	0.60918	-0.5955
28	100	Unbiased-100k	0.60759	0.60568	-1.9121
29	110	Biased-100k	0.60584	0.59322	-12.614
30	110	Biased-100k	0.59573	0.58651	-9.2246
31	110	Biased-100k	0.60444	0.59439	-10.051
32	110	Biased-100k	0.59975	0.59795	-1.8082
34	110	Biased-100k	0.60997	0.59634	-13.63

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60455	0.60562	0.60637	0.00095231	0.60496	0.60582	0.60651	0.0007898	0.0336	0.19543	0.4087	0.19277
50	0.60217	0.60477	0.60842	0.0029119	0.60189	0.60446	0.60774	0.002919	-0.8108	-0.30776	0.4017	0.55609
60	0.60369	0.60614	0.61135	0.0033066	0.59764	0.60039	0.60636	0.0036118	-6.2922	-5.7543	-4.9944	0.52093
100	0.60042	0.60694	0.60977	0.0037267	0.59971	0.60602	0.60918	0.0037411	-1.9121	-0.91632	-0.5102	0.57126
110	0.59573	0.60315	0.60997	0.005521	0.58651	0.59368	0.59795	0.0043987	-13.63	-9.4654	-1.8082	4.6445

Device Test: 33.5 EN_VTH_FALLING(Enable|FallingThreshold/EN1/3/3///90.9/634//0///@EN_VTH_FALLING)





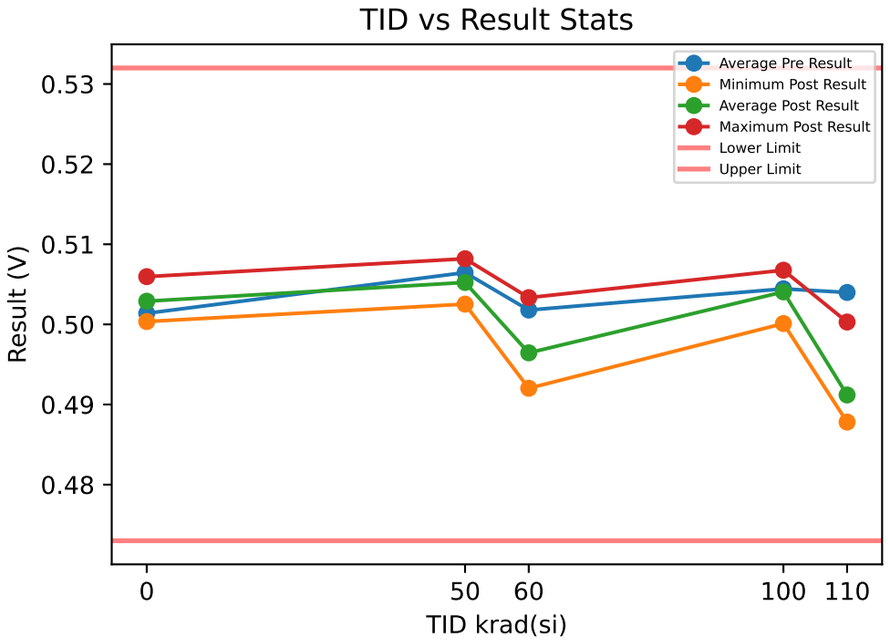
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

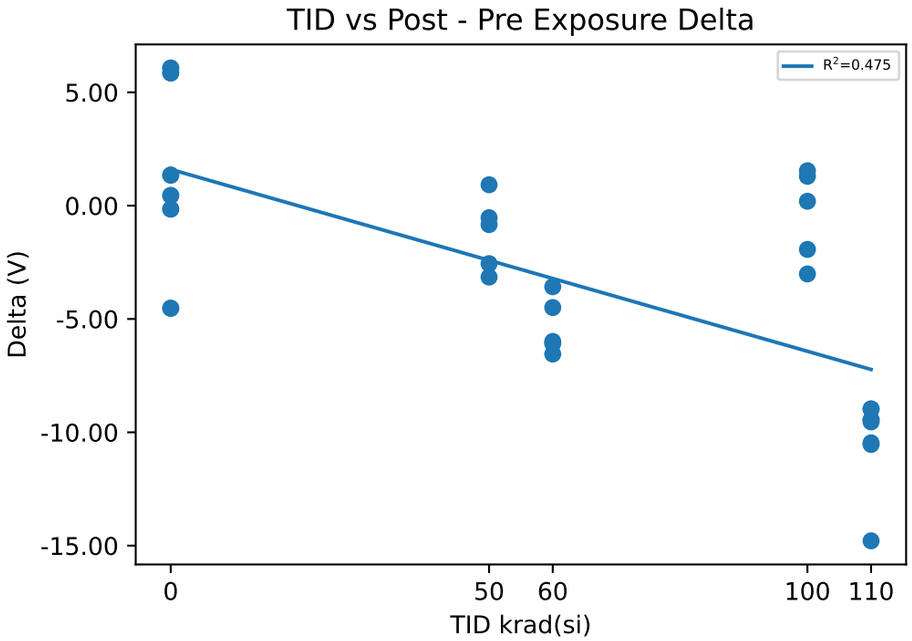
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.50031	0.5007	0.3887
2	0	CU2	0.50495	0.50474	-0.2112
3	0	CU3	0.49926	0.50043	1.1703
11	50	Unbiased-50k	0.50404	0.50318	-0.8593
12	50	Unbiased-50k	0.50898	0.50835	-0.6294
13	50	Unbiased-50k	0.50527	0.50267	-2.5994
14	50	Unbiased-50k	0.50402	0.50485	0.8278
16	50	Unbiased-50k	0.51028	0.50701	-3.2637
17	60	Biased-50k	0.5072	0.50341	-3.7885
18	60	Biased-50k	0.50456	0.49852	-6.0344
19	60	Biased-50k	0.49851	0.49188	-6.6362
20	60	Biased-50k	0.50125	0.49515	-6.1061
21	60	Biased-50k	0.49816	0.49345	-4.7081
24	100	Unbiased-100k	0.50766	0.50444	-3.2125
25	100	Unbiased-100k	0.50208	0.50324	1.1604
26	100	Unbiased-100k	0.50651	0.50662	0.1118
27	100	Unbiased-100k	0.50431	0.50571	1.3983
28	100	Unbiased-100k	0.50227	0.50026	-2.0083
29	110	Biased-100k	0.49892	0.48808	-10.845
30	110	Biased-100k	0.51012	0.50038	-9.7371
31	110	Biased-100k	0.5073	0.49677	-10.529
32	110	Biased-100k	0.50725	0.49211	-15.139
34	110	Biased-100k	0.49722	0.48819	-9.033

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.49926	0.50151	0.50495	0.0030316	0.50043	0.50196	0.50474	0.0024176	-0.2112	0.44927	1.1703	0.69274
50	0.50402	0.50652	0.51028	0.0029213	0.50267	0.50521	0.50835	0.0024385	-3.2637	-1.3048	0.8278	1.6368
60	0.49816	0.50194	0.5072	0.0039054	0.49188	0.49648	0.50341	0.0045915	-6.6362	-5.4547	-3.7885	1.1715
100	0.50208	0.50456	0.50766	0.0024912	0.50026	0.50405	0.50662	0.0024762	-3.2125	-0.51006	1.3983	2.0228
110	0.49722	0.50416	0.51012	0.0057119	0.48808	0.49311	0.50038	0.0054057	-15.139	-11.057	-9.033	2.389

Device Test: 33.6 EN_VTH_FALLING(Enable|FallingThreshold/EN2/3/3///90.9/634//0///@EN_VTH_FALLING)





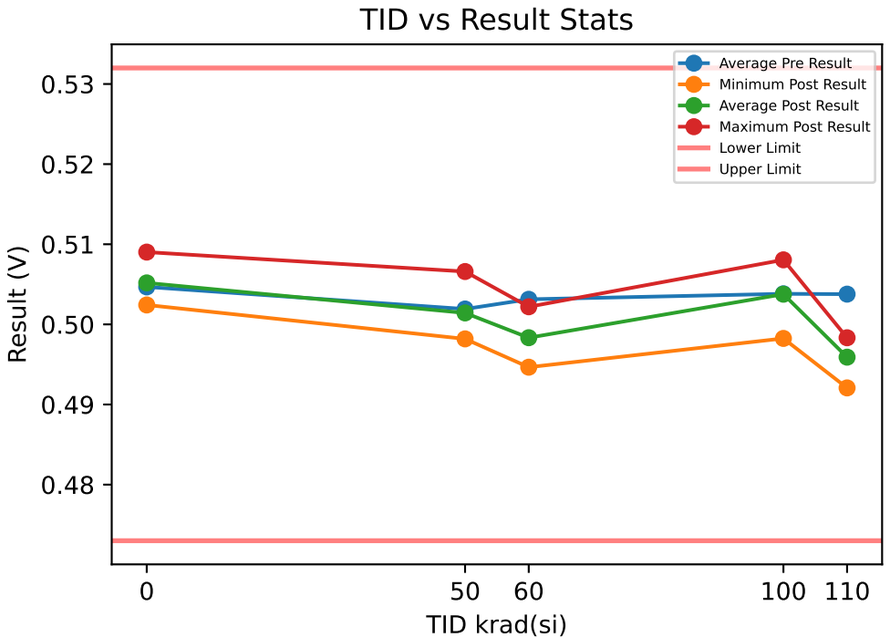
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

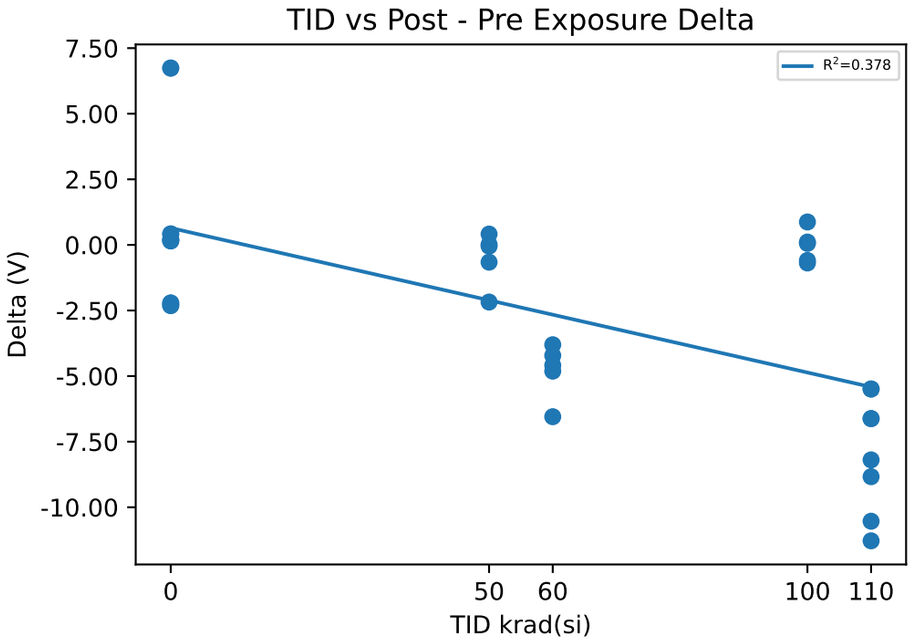
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.5001	0.50055	0.4464
2	0	CU2	0.50504	0.50489	-0.1505
3	0	CU3	0.49901	0.50035	1.3461
11	50	Unbiased-50k	0.5041	0.50326	-0.837
12	50	Unbiased-50k	0.50873	0.50819	-0.5326
13	50	Unbiased-50k	0.50509	0.50253	-2.5588
14	50	Unbiased-50k	0.50409	0.50501	0.9217
16	50	Unbiased-50k	0.51031	0.50716	-3.1524
17	60	Biased-50k	0.50692	0.50334	-3.5775
18	60	Biased-50k	0.50457	0.49857	-5.9921
19	60	Biased-50k	0.49857	0.49203	-6.5468
20	60	Biased-50k	0.50101	0.49493	-6.0853
21	60	Biased-50k	0.49787	0.49338	-4.4961
24	100	Unbiased-100k	0.50746	0.50444	-3.0129
25	100	Unbiased-100k	0.5018	0.5031	1.2957
26	100	Unbiased-100k	0.50657	0.50676	0.1943
27	100	Unbiased-100k	0.50433	0.50587	1.5387
28	100	Unbiased-100k	0.50204	0.50011	-1.9319
29	110	Biased-100k	0.49875	0.48821	-10.536
30	110	Biased-100k	0.50983	0.50029	-9.5412
31	110	Biased-100k	0.50709	0.49662	-10.466
32	110	Biased-100k	0.50699	0.4922	-14.788
34	110	Biased-100k	0.49726	0.48829	-8.9704

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.49901	0.50138	0.50504	0.0032131	0.50035	0.50193	0.50489	0.0025635	-0.1505	0.54733	1.3461	0.75339
50	0.50409	0.50646	0.51031	0.0028743	0.50253	0.50523	0.50819	0.0024359	-3.1524	-1.2318	0.9217	1.638
60	0.49787	0.50179	0.50692	0.0038819	0.49203	0.49645	0.50334	0.0045635	-6.5468	-5.3396	-3.5775	1.2506
100	0.5018	0.50444	0.50746	0.0025687	0.50011	0.50406	0.50676	0.0026122	-3.0129	-0.38322	1.5387	2.01
110	0.49726	0.50398	0.50983	0.0056022	0.48821	0.49312	0.50029	0.0052915	-14.788	-10.86	-8.9704	2.2912

Device Test: 33.7 EN_VTH_FALLING(Enable|FallingThreshold/EN3/3/3///90.9/634//0///@EN_VTH_FALLING)





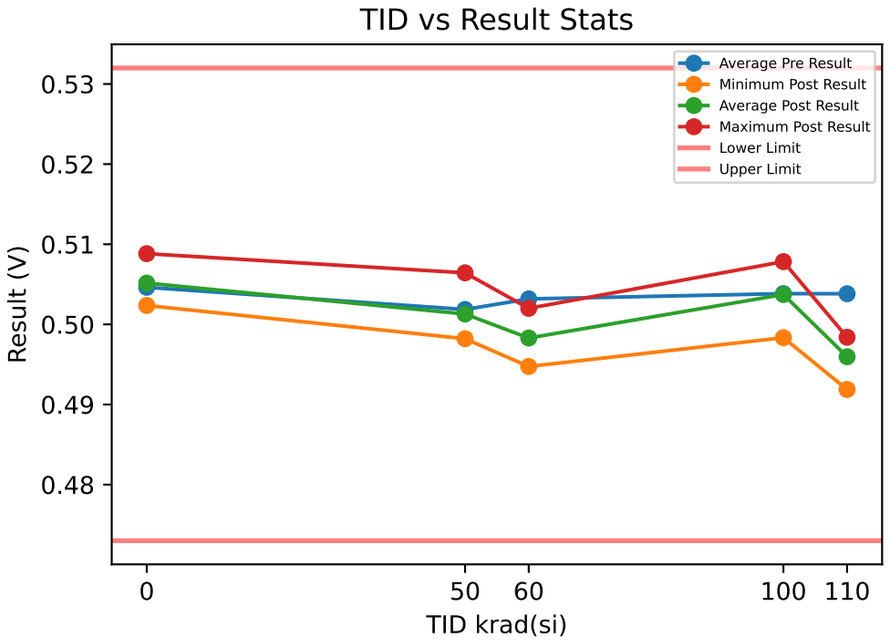
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

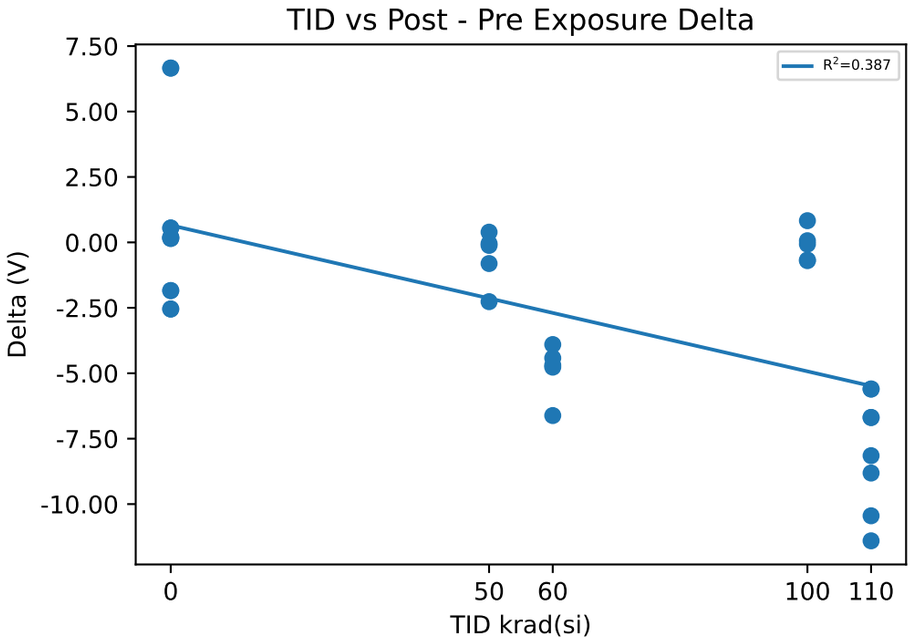
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.50228	0.50243	0.1521
2	0	CU2	0.50473	0.50495	0.2123
3	0	CU3	0.50702	0.50744	0.4169
11	50	Unbiased-50k	0.5015	0.49932	-2.1785
12	50	Unbiased-50k	0.50026	0.50028	0.0185
13	50	Unbiased-50k	0.50341	0.50275	-0.658
14	50	Unbiased-50k	0.50618	0.5066	0.4121
16	50	Unbiased-50k	0.49824	0.49819	-0.0487
17	60	Biased-50k	0.49947	0.49466	-4.8115
18	60	Biased-50k	0.50202	0.49547	-6.5486
19	60	Biased-50k	0.50442	0.5002	-4.2174
20	60	Biased-50k	0.50679	0.5022	-4.5899
21	60	Biased-50k	0.50296	0.49916	-3.8051
24	100	Unbiased-100k	0.49814	0.49825	0.1087
25	100	Unbiased-100k	0.50201	0.50207	0.0581
26	100	Unbiased-100k	0.50562	0.50503	-0.5929
27	100	Unbiased-100k	0.50612	0.50543	-0.6894
28	100	Unbiased-100k	0.50718	0.50806	0.8736
29	110	Biased-100k	0.5039	0.49336	-10.532
30	110	Biased-100k	0.50471	0.49588	-8.8345
31	110	Biased-100k	0.50335	0.49207	-11.279
32	110	Biased-100k	0.50309	0.49489	-8.1945
34	110	Biased-100k	0.50382	0.49833	-5.4927

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.50228	0.50468	0.50702	0.0023699	0.50243	0.50494	0.50744	0.0025019	0.1521	0.26043	0.4169	0.13881
50	0.49824	0.50192	0.50618	0.0030372	0.49819	0.50143	0.5066	0.0033433	-2.1785	-0.49092	0.4121	1.0181
60	0.49947	0.50313	0.50679	0.0027257	0.49466	0.49834	0.5022	0.0031951	-6.5486	-4.7945	-3.8051	1.0525
100	0.49814	0.50382	0.50718	0.0037219	0.49825	0.50377	0.50806	0.0037455	-0.6894	-0.04838	0.8736	0.63116
110	0.50309	0.50377	0.50471	0.00062206	0.49207	0.49491	0.49833	0.0024015	-11.279	-8.8667	-5.4927	2.2601

Device Test: 33.8 EN_VTH_FALLING(Enable|FallingThreshold/EN4/3/3///90.9/634//0///@EN_VTH_FALLING)





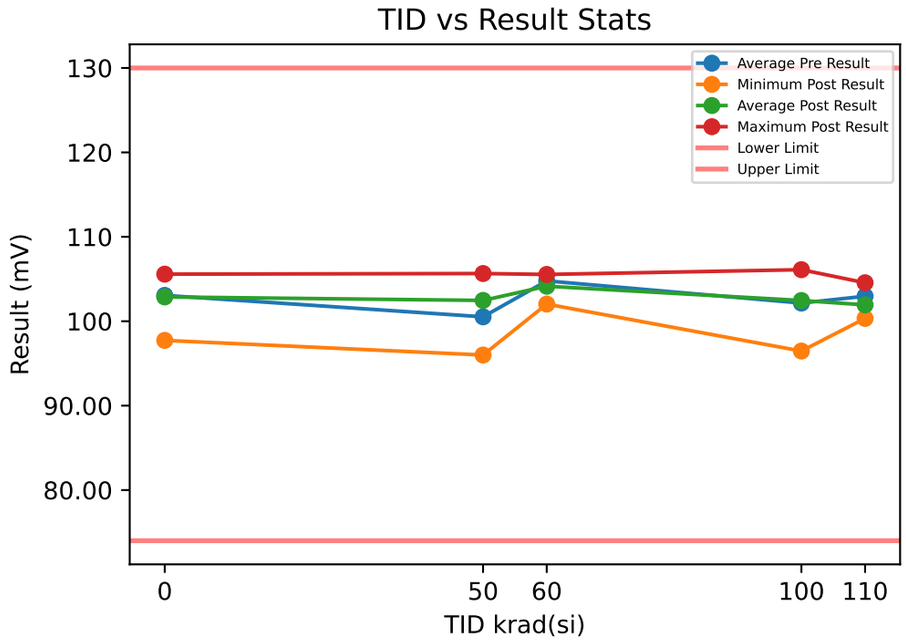
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

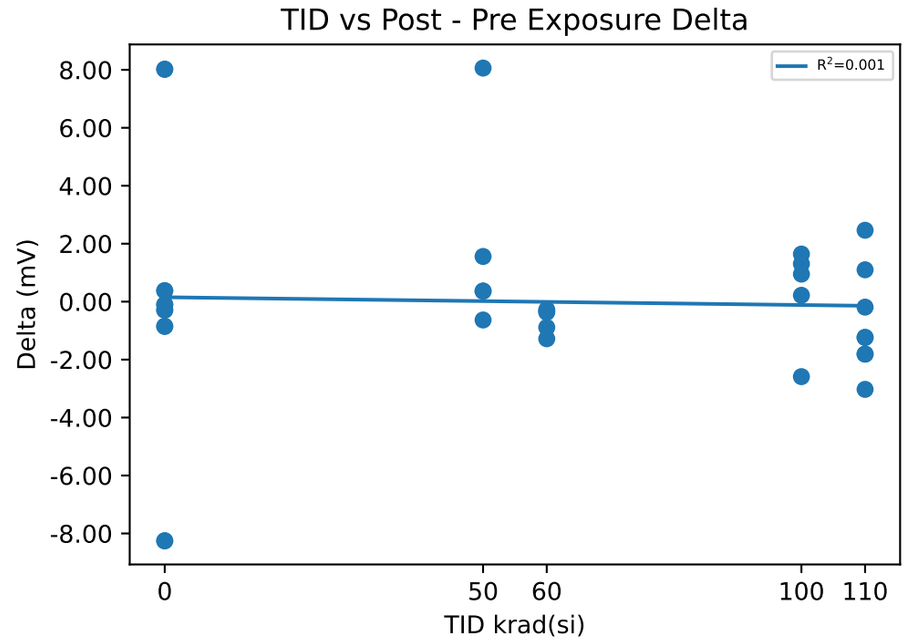
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.50217	0.50236	0.1979
2	0	CU2	0.5049	0.50506	0.1516
3	0	CU3	0.50681	0.50736	0.5486
11	50	Unbiased-50k	0.50144	0.49917	-2.265
12	50	Unbiased-50k	0.50012	0.50008	-0.0423
13	50	Unbiased-50k	0.50337	0.50257	-0.808
14	50	Unbiased-50k	0.50604	0.50643	0.3906
16	50	Unbiased-50k	0.49833	0.49821	-0.1154
17	60	Biased-50k	0.49951	0.49474	-4.7669
18	60	Biased-50k	0.50218	0.49556	-6.6163
19	60	Biased-50k	0.50437	0.49995	-4.4192
20	60	Biased-50k	0.50669	0.502	-4.6898
21	60	Biased-50k	0.50313	0.49923	-3.9038
24	100	Unbiased-100k	0.49828	0.49834	0.0632
25	100	Unbiased-100k	0.50217	0.50211	-0.0674
26	100	Unbiased-100k	0.5055	0.50482	-0.6764
27	100	Unbiased-100k	0.50623	0.50553	-0.6973
28	100	Unbiased-100k	0.507	0.50783	0.8286
29	110	Biased-100k	0.50373	0.49328	-10.446
30	110	Biased-100k	0.50488	0.49607	-8.8129
31	110	Biased-100k	0.50328	0.49188	-11.403
32	110	Biased-100k	0.50323	0.49508	-8.1494
34	110	Biased-100k	0.50399	0.49839	-5.6027

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.50217	0.50463	0.50681	0.002334	0.50236	0.50493	0.50736	0.0024995	0.1516	0.29937	0.5486	0.21708
50	0.49833	0.50186	0.50604	0.0029769	0.49821	0.50129	0.50643	0.0032968	-2.265	-0.56802	0.3906	1.0413
60	0.49951	0.50318	0.50669	0.0026562	0.49474	0.4983	0.502	0.0030593	-6.6163	-4.8792	-3.9038	1.0282
100	0.49828	0.50384	0.507	0.0036115	0.49834	0.50373	0.50783	0.0036376	-0.6973	-0.10986	0.8286	0.62819
110	0.50323	0.50382	0.50488	0.00067267	0.49188	0.49494	0.49839	0.0025171	-11.403	-8.8828	-5.6027	2.2414

Device Test: 33.9 EN_VTH_HYST(Enable|Hys/EN1/3/3///90.9/634//0///@EN_VTH_HYST)





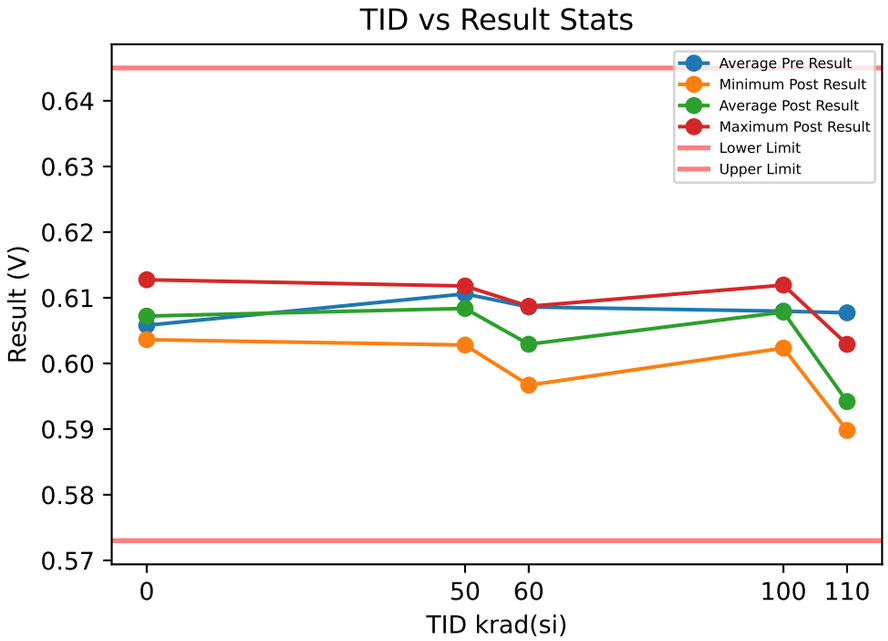
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

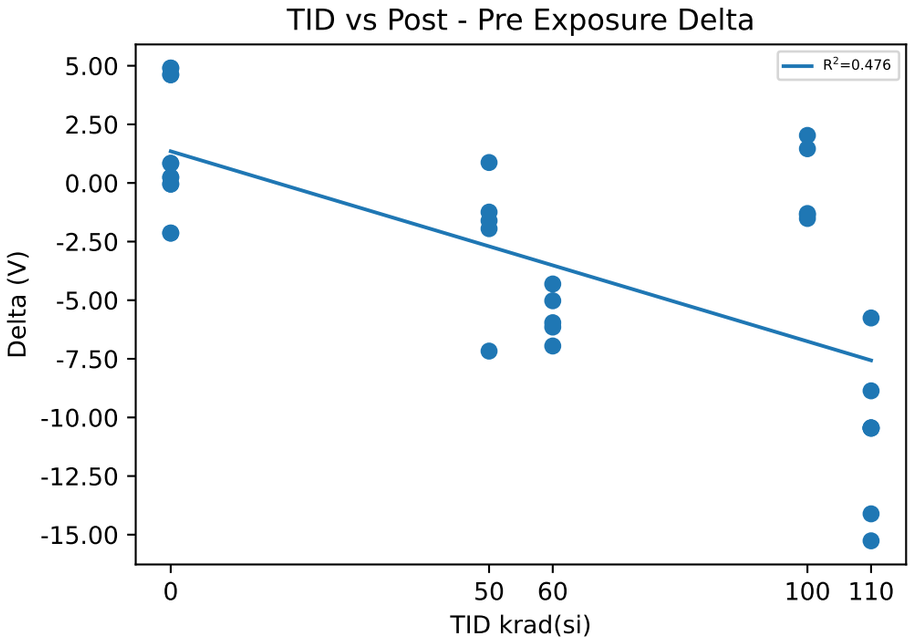
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	105.64	105.54	-0.1026
2	0	CU2	97.556	97.933	0.3774
3	0	CU3	105.99	105.14	-0.851
11	50	Unbiased-50k	102.95	102.32	-0.6326
12	50	Unbiased-50k	97.389	105.45	8.0609
13	50	Unbiased-50k	105.28	105.65	0.3669
14	50	Unbiased-50k	95.636	95.998	0.3617
16	50	Unbiased-50k	101.35	102.91	1.5591
17	60	Biased-50k	103.31	102.03	-1.2805
18	60	Biased-50k	104.81	104.48	-0.3306
19	60	Biased-50k	104.03	103.66	-0.3668
20	60	Biased-50k	105.82	105.54	-0.2763
21	60	Biased-50k	105.91	105.02	-0.8884
24	100	Unbiased-100k	103.16	104.8	1.642
25	100	Unbiased-100k	105.15	106.1	0.95
26	100	Unbiased-100k	97.726	99.032	1.3059
27	100	Unbiased-100k	99.056	96.468	-2.588
28	100	Unbiased-100k	105.66	105.88	0.2198
29	110	Biased-100k	106.45	103.42	-3.027
30	110	Biased-100k	100.24	101.34	1.0996
31	110	Biased-100k	104.75	104.56	-0.1892
32	110	Biased-100k	101.24	103.7	2.4641
34	110	Biased-100k	102.14	100.33	-1.8097

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.556	103.06	105.99	4.7719	97.933	102.87	105.54	4.2804	-0.851	-0.19207	0.3774	0.61907
50	95.636	100.52	105.28	3.9669	95.998	102.47	105.65	3.9082	-0.6326	1.9432	8.0609	3.5069
60	103.31	104.78	105.91	1.1273	102.03	104.15	105.54	1.373	-1.2805	-0.62852	-0.2763	0.43987
100	97.726	102.15	105.66	3.5874	96.468	102.46	106.1	4.4179	-2.588	0.30594	1.642	1.7016
110	100.24	102.96	106.45	2.5701	100.33	102.67	104.56	1.7627	-3.027	-0.29244	2.4641	2.1981

Device Test: 34.1 EN_VTH_RISING(Enable|RisingThreshold/EN1/7/7///90.9/634//0///@EN_VTH_RISING)





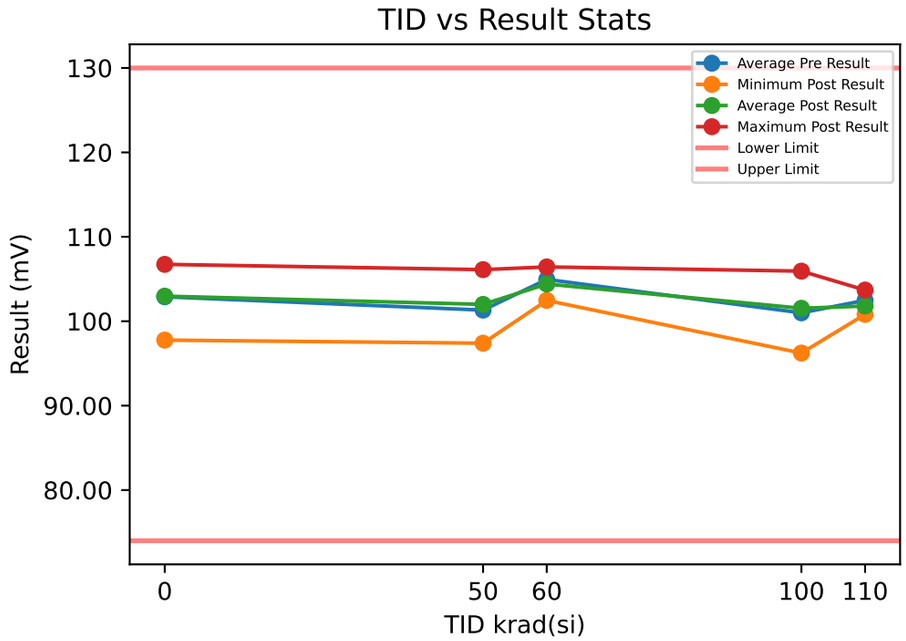
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

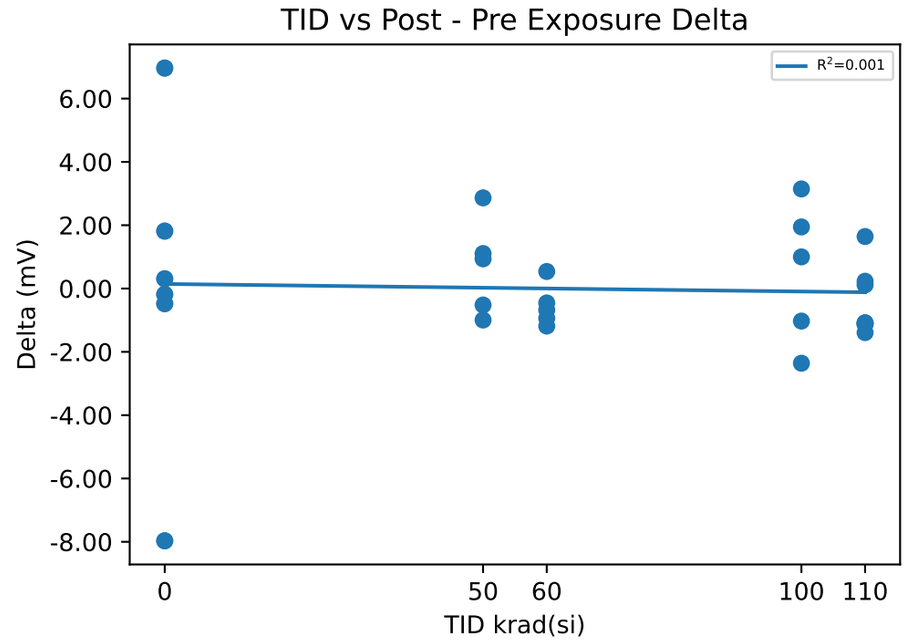
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.60784	0.60808	0.241
2	0	CU2	0.60367	0.60362	-0.0477
3	0	CU3	0.60591	0.60674	0.8357
11	50	Unbiased-50k	0.60885	0.60761	-1.2418
12	50	Unbiased-50k	0.61588	0.60871	-7.1702
13	50	Unbiased-50k	0.61291	0.61096	-1.9491
14	50	Unbiased-50k	0.60193	0.6028	0.8723
16	50	Unbiased-50k	0.6134	0.61179	-1.6072
17	60	Biased-50k	0.61301	0.6087	-4.3085
18	60	Biased-50k	0.6116	0.60545	-6.1457
19	60	Biased-50k	0.60365	0.5967	-6.953
20	60	Biased-50k	0.60886	0.6029	-5.9591
21	60	Biased-50k	0.60589	0.60087	-5.0245
24	100	Unbiased-100k	0.61182	0.6103	-1.514
25	100	Unbiased-100k	0.60991	0.61194	2.0285
26	100	Unbiased-100k	0.60449	0.60595	1.4605
27	100	Unbiased-100k	0.60369	0.60234	-1.3553
28	100	Unbiased-100k	0.60989	0.60859	-1.3032
29	110	Biased-100k	0.60726	0.592	-15.262
30	110	Biased-100k	0.61171	0.60285	-8.8653
31	110	Biased-100k	0.60866	0.6029	-5.7573
32	110	Biased-100k	0.61068	0.59657	-14.112
34	110	Biased-100k	0.60025	0.5898	-10.445

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60367	0.60581	0.60784	0.0020877	0.60362	0.60615	0.60808	0.0022886	-0.0477	0.343	0.8357	0.45045
50	0.60193	0.6106	0.61588	0.0054616	0.6028	0.60838	0.61179	0.0035398	-7.1702	-2.2192	0.8723	2.9779
60	0.60365	0.6086	0.61301	0.0038828	0.5967	0.60292	0.6087	0.0045478	-6.953	-5.6782	-4.3085	1.0279
100	0.60369	0.60796	0.61182	0.0036273	0.60234	0.60782	0.61194	0.0037826	-1.514	-0.1367	2.0285	1.7307
110	0.60025	0.60771	0.61171	0.004518	0.5898	0.59682	0.6029	0.0060396	-15.262	-10.888	-5.7573	3.8774

Device Test: 34.10 EN_VTH_HYST(Enable|Hys/EN2/7/7///90.9/634//0///@EN_VTH_HYST)





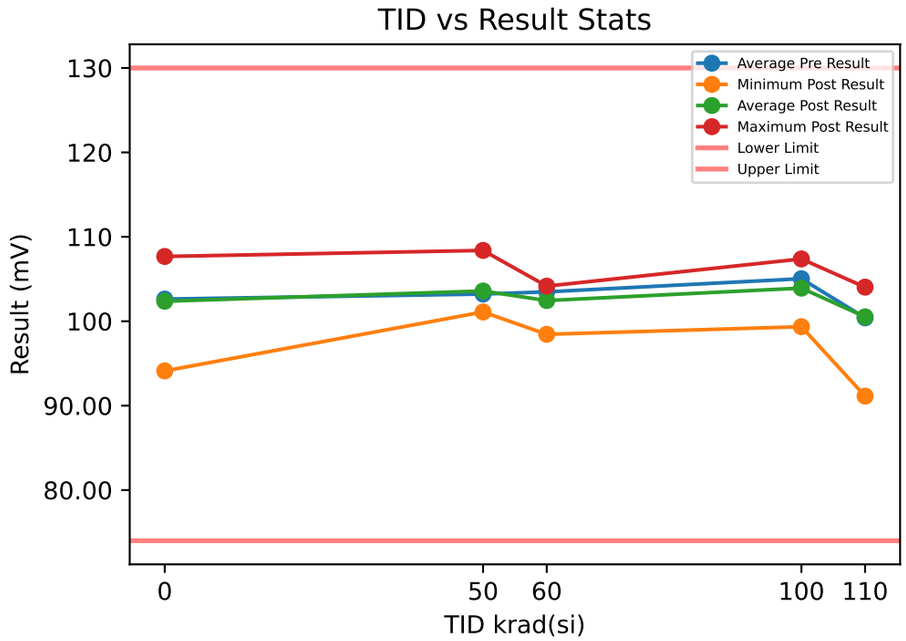
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

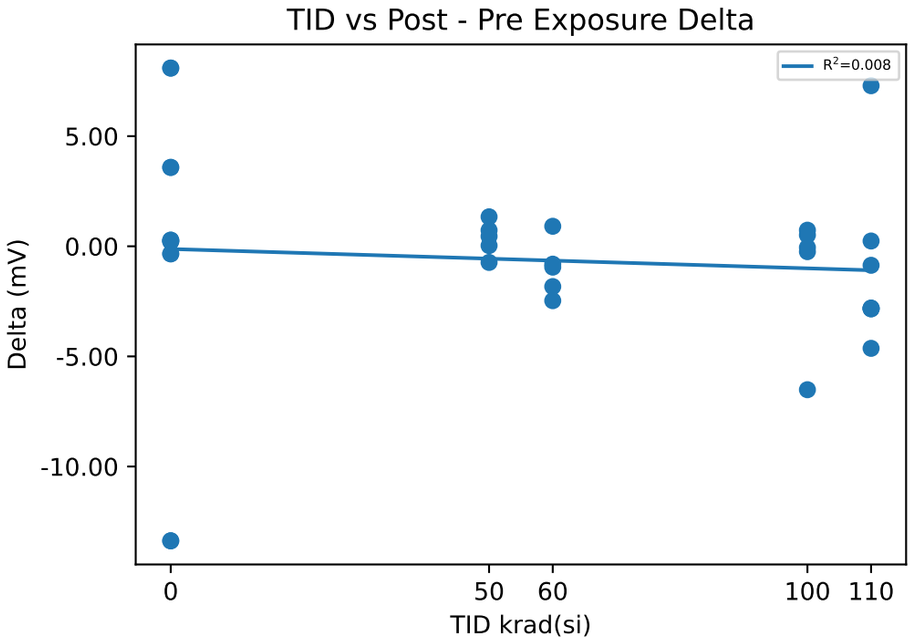
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	104.92	104.45	-0.4774
2	0	CU2	97.95	97.765	-0.185
3	0	CU3	105.81	106.12	0.3076
11	50	Unbiased-50k	103.25	106.11	2.8641
12	50	Unbiased-50k	99.827	98.833	-0.9946
13	50	Unbiased-50k	103.61	104.55	0.9373
14	50	Unbiased-50k	97.919	97.398	-0.5202
16	50	Unbiased-50k	101.98	103.08	1.1051
17	60	Biased-50k	106.19	105	-1.1852
18	60	Biased-50k	105.89	106.43	0.5381
19	60	Biased-50k	104.19	103.52	-0.6789
20	60	Biased-50k	102.92	102.47	-0.455
21	60	Biased-50k	105.57	104.63	-0.9372
24	100	Unbiased-100k	104.94	105.94	0.9995
25	100	Unbiased-100k	103.15	102.12	-1.028
26	100	Unbiased-100k	97.181	99.127	1.9455
27	100	Unbiased-100k	98.591	96.231	-2.3593
28	100	Unbiased-100k	101.11	104.26	3.1457
29	110	Biased-100k	105.08	103.69	-1.392
30	110	Biased-100k	101.27	101.39	0.1144
31	110	Biased-100k	101.15	102.8	1.6432
32	110	Biased-100k	102.92	103.15	0.2303
34	110	Biased-100k	101.94	100.81	-1.1248

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.95	102.9	105.81	4.3066	97.765	102.78	106.12	4.4215	-0.4774	-0.11827	0.3076	0.39673
50	97.919	101.32	103.61	2.4085	97.398	102	106.11	3.7347	-0.9946	0.67834	2.8641	1.5217
60	102.92	104.95	106.19	1.3689	102.47	104.41	106.43	1.5058	-1.1852	-0.54364	0.5381	0.66385
100	97.181	100.99	104.94	3.1825	96.231	101.53	105.94	3.9067	-2.3593	0.54068	3.1457	2.2272
110	101.15	102.47	105.08	1.6198	100.81	102.37	103.69	1.2184	-1.392	-0.10578	1.6432	1.2158

Device Test: 34.11 EN_VTH_HYST(Enable|Hys/EN3/7/7///90.9/634//0///@EN_VTH_HYST)





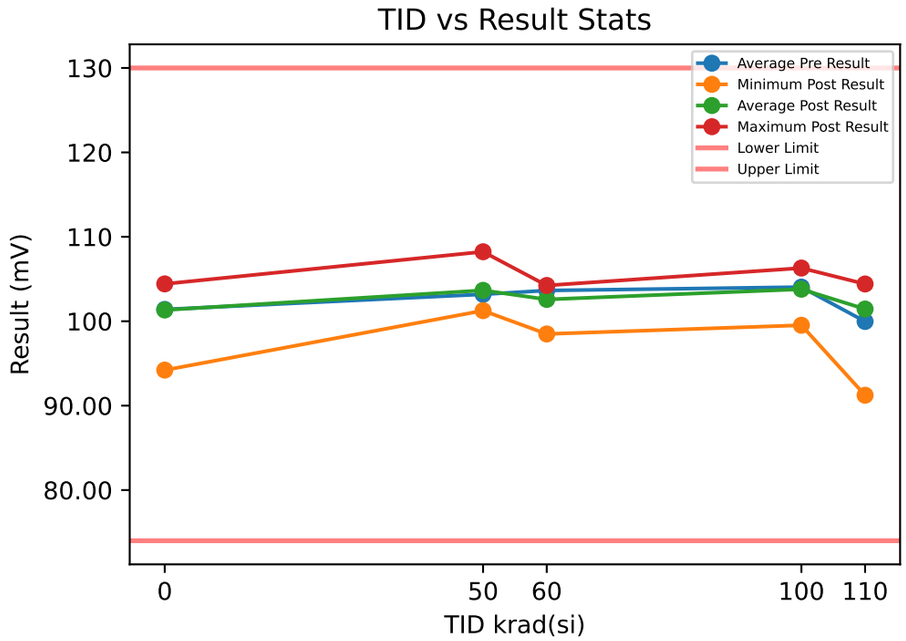
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

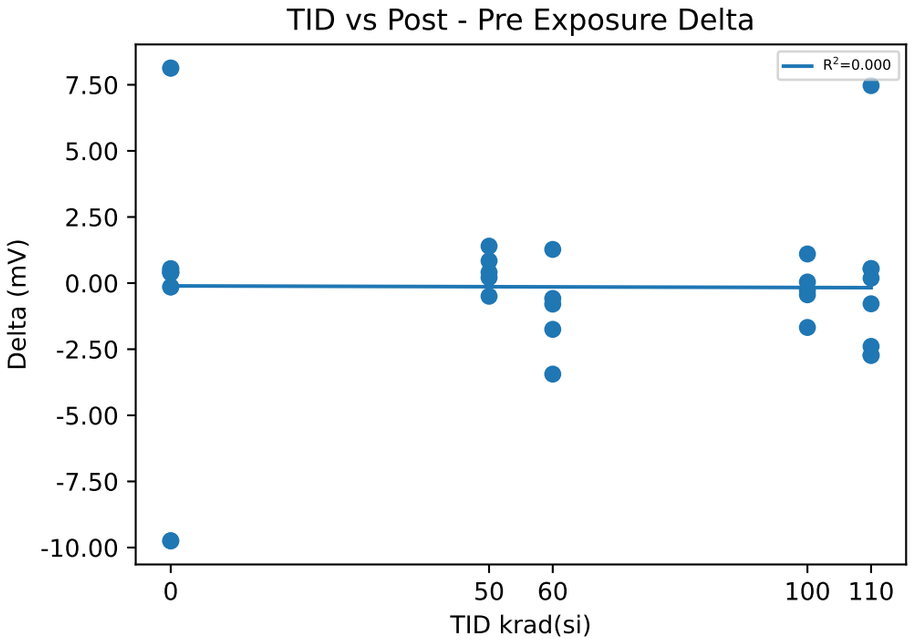
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	107.49	107.15	-0.3429
2	0	CU2	104.09	104.31	0.2203
3	0	CU3	96.294	96.571	0.2769
11	50	Unbiased-50k	101.37	102.7	1.3385
12	50	Unbiased-50k	102.22	101.48	-0.7335
13	50	Unbiased-50k	107.93	108.39	0.4522
14	50	Unbiased-50k	100.37	101.1	0.7285
16	50	Unbiased-50k	104.2	104.24	0.0318
17	60	Biased-50k	104.24	103.42	-0.8113
18	60	Biased-50k	101.78	102.69	0.9081
19	60	Biased-50k	100.28	98.449	-1.8297
20	60	Biased-50k	105.11	104.16	-0.9473
21	60	Biased-50k	105.99	103.51	-2.4704
24	100	Unbiased-100k	102	102.73	0.731
25	100	Unbiased-100k	106.87	107.38	0.5092
26	100	Unbiased-100k	104.39	104.34	-0.0558
27	100	Unbiased-100k	106.06	105.82	-0.2447
28	100	Unbiased-100k	105.86	99.35	-6.5129
29	110	Biased-100k	106.41	101.77	-4.6343
30	110	Biased-100k	91.99	91.127	-0.8634
31	110	Biased-100k	103.06	103.3	0.239
32	110	Biased-100k	96.747	104.04	7.2898
34	110	Biased-100k	103.81	101	-2.8091

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	96.294	102.62	107.49	5.7402	96.571	102.68	107.15	5.4744	-0.3429	0.051433	0.2769	0.34267
50	100.37	103.22	107.93	2.9899	101.1	103.58	108.39	2.9516	-0.7335	0.3635	1.3385	0.77543
60	100.28	103.48	105.99	2.3777	98.449	102.45	104.16	2.2952	-2.4704	-1.0301	0.9081	1.2772
100	102	105.04	106.87	1.921	99.35	103.92	107.38	3.0846	-6.5129	-1.1146	0.731	3.0439
110	91.99	100.4	106.41	5.8924	91.127	100.25	104.04	5.2386	-4.6343	-0.1556	7.2898	4.5604

Device Test: 34.12 EN_VTH_HYST(Enable|Hys/EN4/7/7///90.9/634//0///@EN_VTH_HYST)





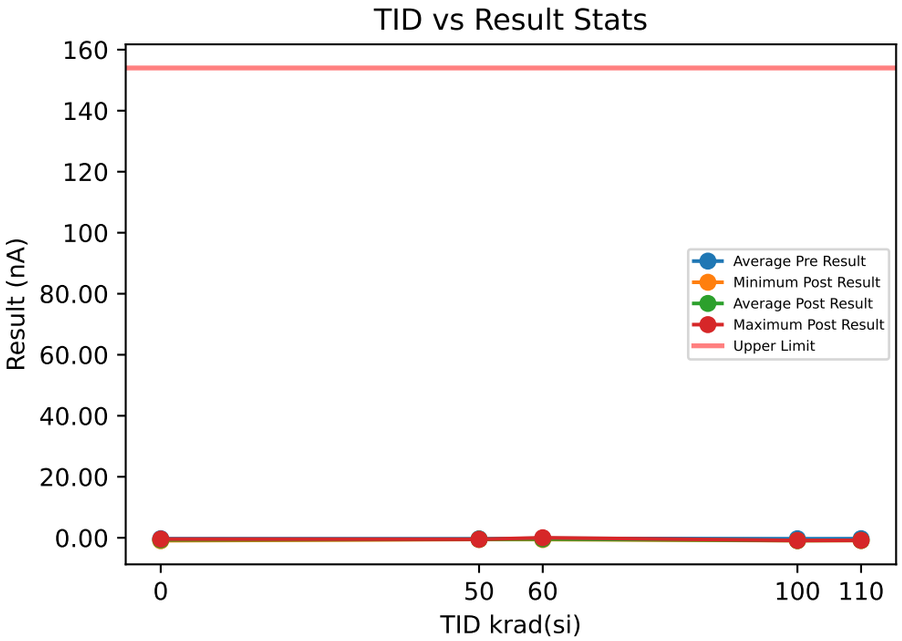
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

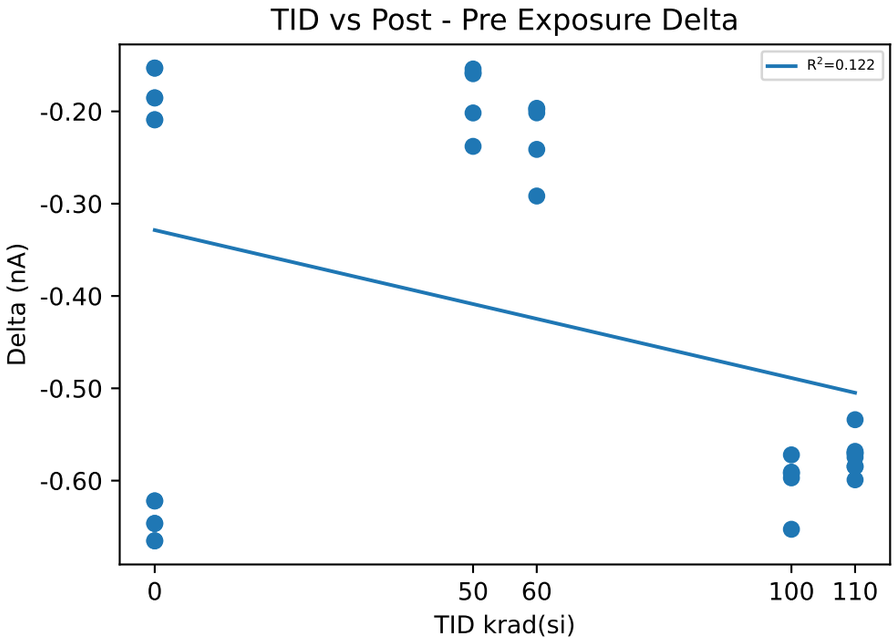
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	103.96	103.81	-0.1447
2	0	CU2	104	104.39	0.3889
3	0	CU3	96.242	96.785	0.5424
11	50	Unbiased-50k	101.34	102.73	1.3975
12	50	Unbiased-50k	102.19	101.7	-0.4968
13	50	Unbiased-50k	107.82	108.23	0.4072
14	50	Unbiased-50k	100.41	101.25	0.8395
16	50	Unbiased-50k	104.16	104.37	0.2092
17	60	Biased-50k	104.29	103.71	-0.5806
18	60	Biased-50k	101.64	102.91	1.2737
19	60	Biased-50k	100.24	98.492	-1.7496
20	60	Biased-50k	105.03	104.24	-0.7939
21	60	Biased-50k	107.01	103.57	-3.4415
24	100	Unbiased-100k	101.84	102.95	1.1014
25	100	Unbiased-100k	106.74	106.3	-0.4421
26	100	Unbiased-100k	104.28	104.32	0.0413
27	100	Unbiased-100k	106.15	105.88	-0.2734
28	100	Unbiased-100k	101.2	99.523	-1.6776
29	110	Biased-100k	104.25	101.86	-2.3931
30	110	Biased-100k	92.016	91.233	-0.7824
31	110	Biased-100k	103.1	103.28	0.1856
32	110	Biased-100k	96.628	104.1	7.4681
34	110	Biased-100k	103.86	104.41	0.5473

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	96.242	101.4	104	4.4663	96.785	101.66	104.39	4.2335	-0.1447	0.2622	0.5424	0.36065
50	100.41	103.19	107.82	2.9387	101.25	103.66	108.23	2.8236	-0.4968	0.47132	1.3975	0.70771
60	100.24	103.64	107.01	2.7054	98.492	102.58	104.24	2.335	-3.4415	-1.0584	1.2737	1.7244
100	101.2	104.04	106.74	2.485	99.523	103.79	106.3	2.7324	-1.6776	-0.25008	1.1014	0.99833
110	92.016	99.971	104.25	5.4243	91.233	100.98	104.41	5.5353	-2.3931	1.0051	7.4681	3.788

Device Test: 34.13 EN_LKG_CURR(Enable|LeakageHigh/EN1/7/7///90.9/634//0///@EN_LKG_CURR)





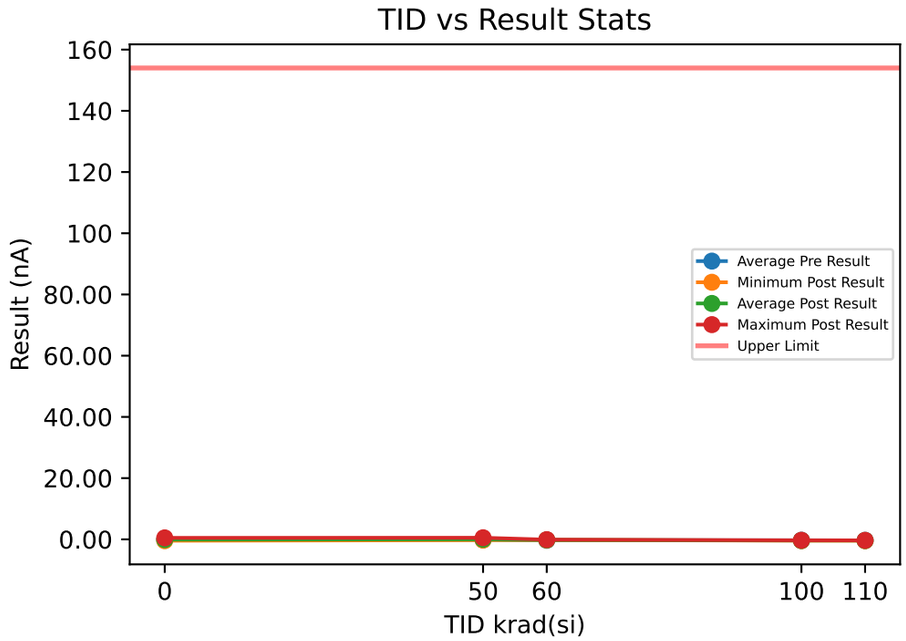
Test Results (Upper Limit = 154.0 (nA))

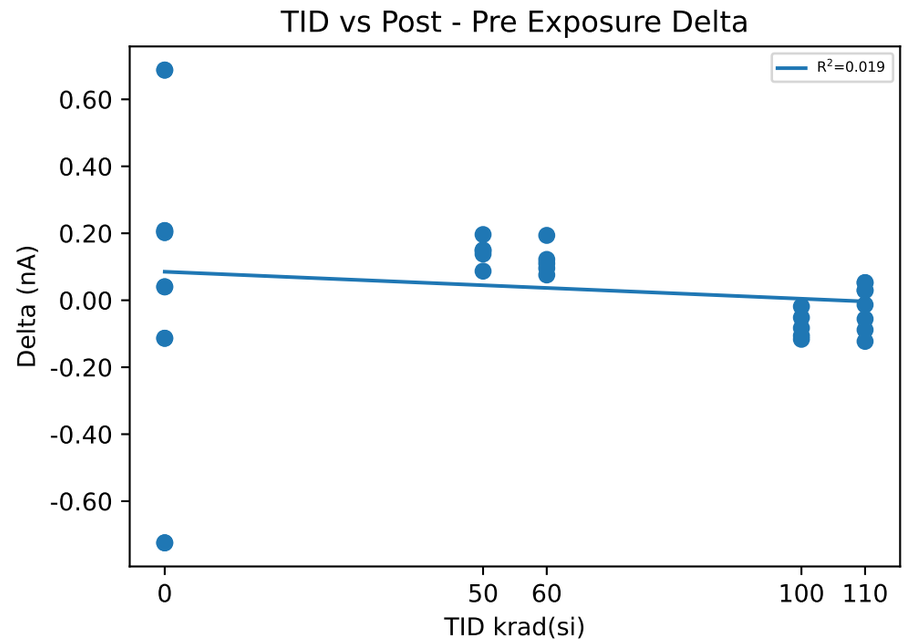
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.2667	-0.4198	-0.1531
2	0	CU2	-0.3074	-0.4928	-0.1854
3	0	CU3	-0.3118	-0.5209	-0.2091
11	50	Unbiased-50k	-0.2924	-0.4941	-0.2017
12	50	Unbiased-50k	-0.3449	-0.5028	-0.1579
13	50	Unbiased-50k	-0.3086	-0.5465	-0.2379
14	50	Unbiased-50k	-0.3568	-0.5109	-0.1541
16	50	Unbiased-50k	-0.3411	-0.5003	-0.1592
17	60	Biased-50k	-0.268	-0.4647	-0.1967
18	60	Biased-50k	-0.2817	-0.5734	-0.2917
19	60	Biased-50k	-0.3368	-0.5346	-0.1978
20	60	Biased-50k	0.2579	0.0167	-0.2412
21	60	Biased-50k	-0.3424	-0.544	-0.2016
24	100	Unbiased-100k	-0.3449	-0.9419	-0.597
25	100	Unbiased-100k	-0.3374	-0.9282	-0.5908
26	100	Unbiased-100k	-0.3255	-0.8976	-0.5721
27	100	Unbiased-100k	-0.2755	-0.9282	-0.6527
28	100	Unbiased-100k	-0.2761	-0.8683	-0.5922
29	110	Biased-100k	-0.3368	-0.9051	-0.5683
30	110	Biased-100k	-0.2305	-0.8296	-0.5991
31	110	Biased-100k	-0.298	-0.8726	-0.5746
32	110	Biased-100k	-0.3411	-0.8751	-0.534
34	110	Biased-100k	-0.2467	-0.8171	-0.5704

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3118	-0.2953	-0.2667	0.024866	-0.5209	-0.47783	-0.4198	0.052185	-0.2091	-0.18253	-0.1531	0.02811
50	-0.3568	-0.32876	-0.2924	0.027053	-0.5465	-0.51092	-0.4941	0.020782	-0.2379	-0.18216	-0.1541	0.036715
60	-0.3424	-0.1942	0.2579	0.25485	-0.5734	-0.42	0.0167	0.24736	-0.2917	-0.2258	-0.1967	0.04122
100	-0.3449	-0.31188	-0.2755	0.033656	-0.9419	-0.91284	-0.8683	0.029717	-0.6527	-0.60096	-0.5721	0.030437
110	-0.3411	-0.29062	-0.2305	0.050692	-0.9051	-0.8599	-0.8171	0.036005	-0.5991	-0.56928	-0.534	0.023262

Device Test: 34.14 EN_LKG_CURR(Enable|LeakageHigh/EN2/7/7///90.9/634//0///@EN_LKG_CURR)





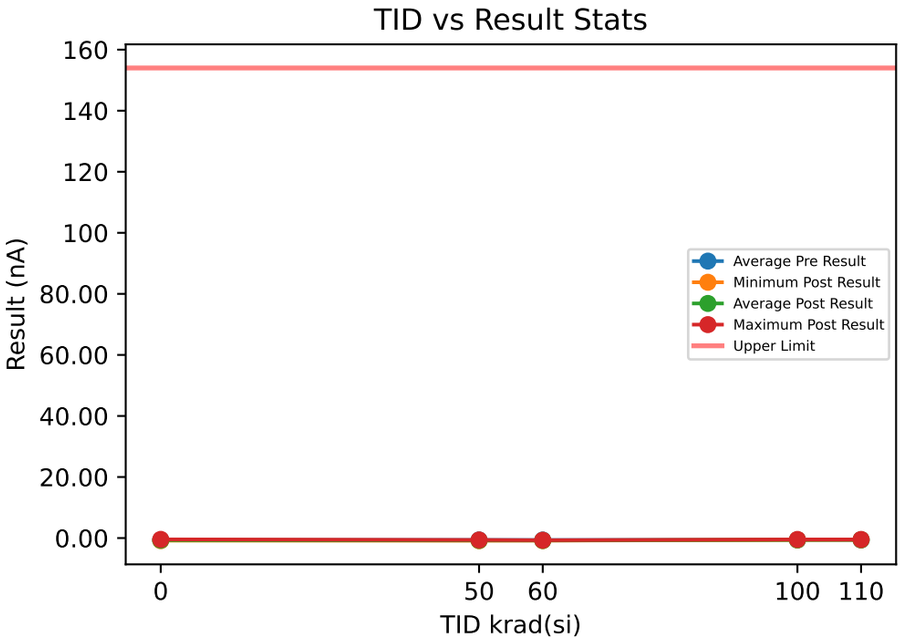
Test Results (Upper Limit = 154.0 (nA))

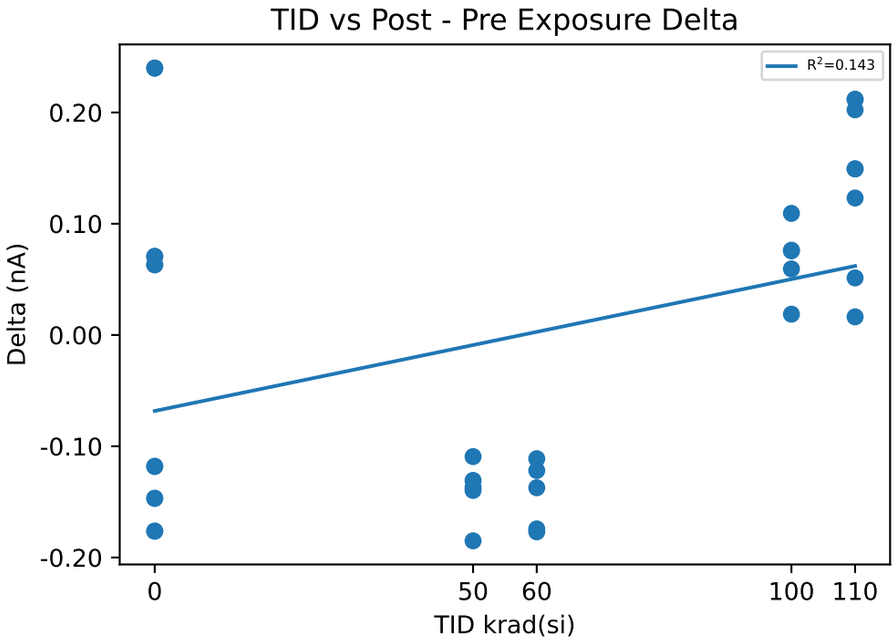
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.3369	-0.2968	0.0401
2	0	CU2	0.2784	0.4808	0.2024
3	0	CU3	-0.3519	-0.1439	0.208
11	50	Unbiased-50k	-0.3581	-0.22	0.1381
12	50	Unbiased-50k	0.3696	0.5195	0.1499
13	50	Unbiased-50k	0.0506	0.2468	0.1962
14	50	Unbiased-50k	-0.3987	-0.2506	0.1481
16	50	Unbiased-50k	-0.3569	-0.27	0.0869
17	60	Biased-50k	-0.1928	-0.0971	0.0957
18	60	Biased-50k	-0.3088	-0.2332	0.0756
19	60	Biased-50k	-0.3382	-0.2163	0.1219
20	60	Biased-50k	-0.3257	-0.2157	0.11
21	60	Biased-50k	-0.3775	-0.1838	0.1937
24	100	Unbiased-100k	-0.3107	-0.4273	-0.1166
25	100	Unbiased-100k	-0.3775	-0.3961	-0.0186
26	100	Unbiased-100k	-0.3619	-0.4136	-0.0517
27	100	Unbiased-100k	-0.2246	-0.3074	-0.0828
28	100	Unbiased-100k	-0.2882	-0.3942	-0.106
29	110	Biased-100k	-0.3638	-0.4198	-0.056
30	110	Biased-100k	-0.2396	-0.328	-0.0884
31	110	Biased-100k	-0.3288	-0.4516	-0.1228
32	110	Biased-100k	-0.3737	-0.3873	-0.0136
34	110	Biased-100k	-0.4168	-0.3642	0.0526

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3519	-0.1368	0.2784	0.35965	-0.2968	0.013367	0.4808	0.41196	0.0401	0.15017	0.208	0.095362
50	-0.3987	-0.1387	0.3696	0.33821	-0.27	0.00514	0.5195	0.35873	0.0869	0.14384	0.1962	0.03896
60	-0.3775	-0.3086	-0.1928	0.069508	-0.2332	-0.18922	-0.0971	0.054507	0.0756	0.11938	0.1937	0.044987
100	-0.3775	-0.31258	-0.2246	0.061208	-0.4273	-0.38772	-0.3074	0.046904	-0.1166	-0.07514	-0.0186	0.040237
110	-0.4168	-0.34454	-0.2396	0.066526	-0.4516	-0.39018	-0.328	0.047957	-0.1228	-0.04564	0.0526	0.068131

Device Test: 34.15 EN_LKG_CURR(Enable|LeakageHigh/EN3/7/7///90.9/634//0///@EN_LKG_CURR)





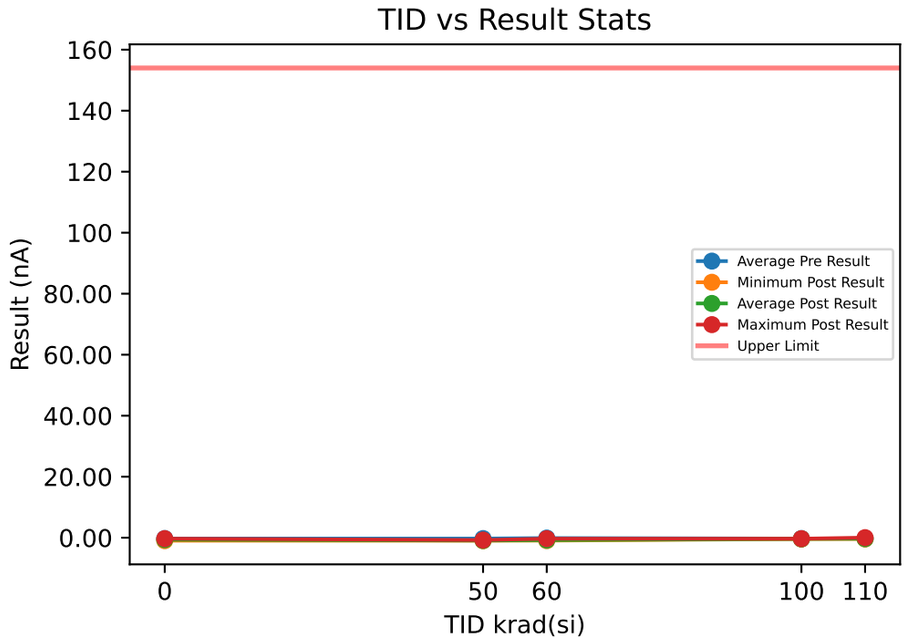
Test Results (Upper Limit = 154.0 (nA))

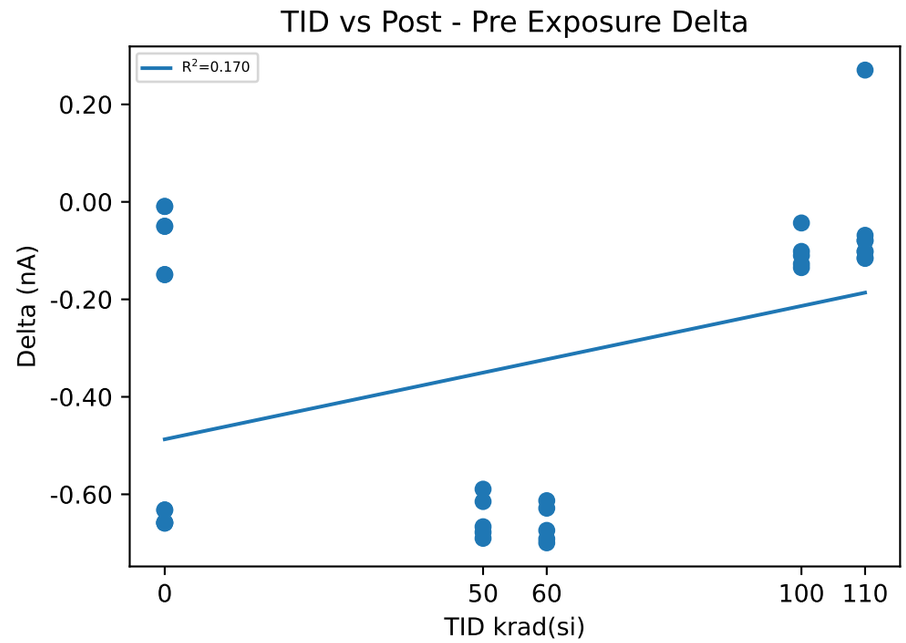
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.6652	-0.8415	-0.1763
2	0	CU2	-0.6908	-0.8089	-0.1181
3	0	CU3	-0.6696	-0.8164	-0.1468
11	50	Unbiased-50k	-0.6846	-0.8696	-0.185
12	50	Unbiased-50k	-0.6521	-0.7614	-0.1093
13	50	Unbiased-50k	-0.4803	-0.62	-0.1397
14	50	Unbiased-50k	-0.7252	-0.8559	-0.1307
16	50	Unbiased-50k	-0.6253	-0.762	-0.1367
17	60	Biased-50k	-0.689	-0.8108	-0.1218
18	60	Biased-50k	-0.6452	-0.8221	-0.1769
19	60	Biased-50k	-0.659	-0.8333	-0.1743
20	60	Biased-50k	-0.5659	-0.7032	-0.1373
21	60	Biased-50k	-0.6946	-0.8058	-0.1112
24	100	Unbiased-100k	-0.6346	-0.5253	0.1093
25	100	Unbiased-100k	-0.6821	-0.6227	0.0594
26	100	Unbiased-100k	-0.5284	-0.4522	0.0762
27	100	Unbiased-100k	-0.6727	-0.5971	0.0756
28	100	Unbiased-100k	-0.6477	-0.629	0.0187
29	110	Biased-100k	-0.6602	-0.4578	0.2024
30	110	Biased-100k	-0.5772	-0.5609	0.0163
31	110	Biased-100k	-0.639	-0.5159	0.1231
32	110	Biased-100k	-0.6509	-0.5996	0.0513
34	110	Biased-100k	-0.6896	-0.4778	0.2118

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.6908	-0.6752	-0.6652	0.013688	-0.8415	-0.82227	-0.8089	0.017073	-0.1763	-0.14707	-0.1181	0.029101
50	-0.7252	-0.6335	-0.4803	0.093412	-0.8696	-0.77378	-0.62	0.099832	-0.185	-0.14028	-0.1093	0.027679
60	-0.6946	-0.65074	-0.5659	0.051682	-0.8333	-0.79504	-0.7032	0.052428	-0.1769	-0.1443	-0.1112	0.030057
100	-0.6821	-0.6331	-0.5284	0.061536	-0.629	-0.56526	-0.4522	0.075424	0.0187	0.06784	0.1093	0.03292
110	-0.6896	-0.64338	-0.5772	0.041457	-0.5996	-0.5224	-0.4578	0.058409	0.0163	0.12098	0.2118	0.0876

Device Test: 34.16 EN_LKG_CURR(Enable|LeakageHigh/EN4/7/7///90.9/634//0///@EN_LKG_CURR)





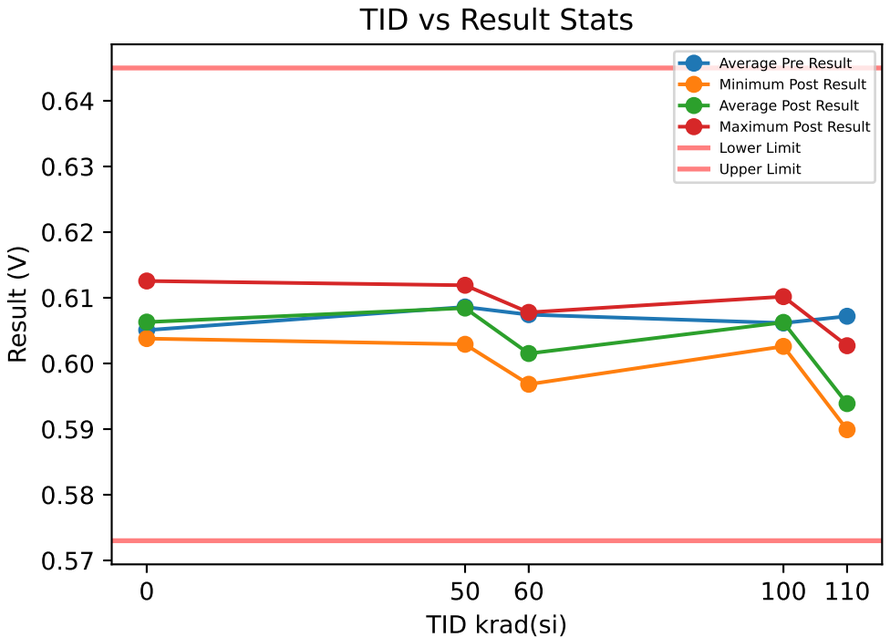
Test Results (Upper Limit = 154.0 (nA))

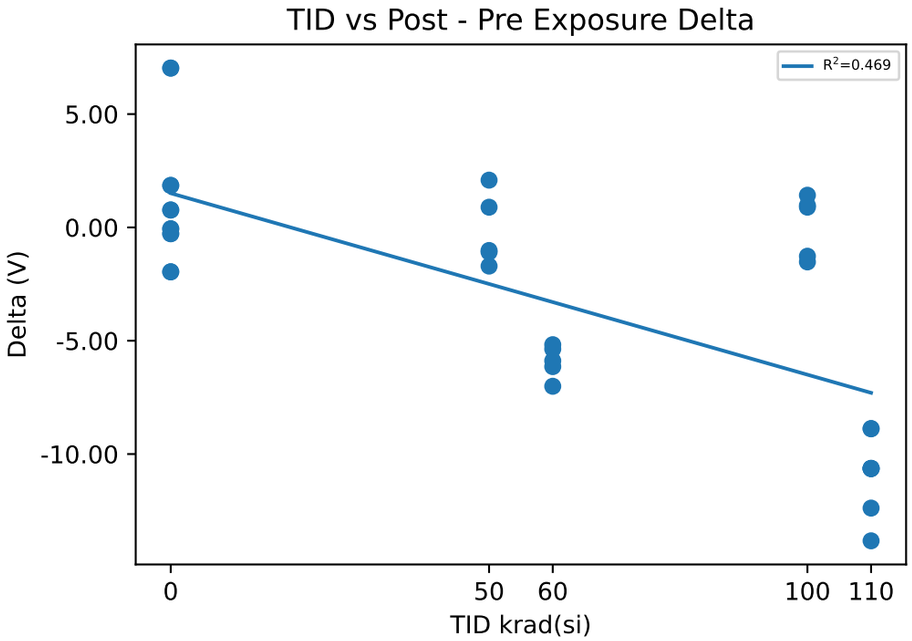
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.2312	-0.8633	-0.6321
2	0	CU2	-0.2929	-0.9519	-0.659
3	0	CU3	-0.3091	-0.9669	-0.6578
11	50	Unbiased-50k	-0.344	-0.9588	-0.6148
12	50	Unbiased-50k	-0.2811	-0.9476	-0.6665
13	50	Unbiased-50k	-0.1746	-0.764	-0.5894
14	50	Unbiased-50k	-0.3004	-0.9782	-0.6778
16	50	Unbiased-50k	-0.2916	-0.9819	-0.6903
17	60	Biased-50k	-0.2742	-0.9482	-0.674
18	60	Biased-50k	0.3734	-0.318	-0.6914
19	60	Biased-50k	-0.3047	-0.9332	-0.6285
20	60	Biased-50k	-0.1553	-0.7683	-0.613
21	60	Biased-50k	-0.2456	-0.9451	-0.6995
24	100	Unbiased-100k	-0.2854	-0.4203	-0.1349
25	100	Unbiased-100k	-0.3159	-0.3592	-0.0433
26	100	Unbiased-100k	-0.3184	-0.4285	-0.1101
27	100	Unbiased-100k	-0.2798	-0.4072	-0.1274
28	100	Unbiased-100k	-0.2157	-0.3173	-0.1016
29	110	Biased-100k	-0.2082	-0.3242	-0.116
30	110	Biased-100k	-0.2699	-0.3848	-0.1149
31	110	Biased-100k	-0.2319	-0.3005	-0.0686
32	110	Biased-100k	-0.2468	0.0236	0.2704
34	110	Biased-100k	-0.306	-0.3854	-0.0794

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3091	-0.27773	-0.2312	0.041105	-0.9669	-0.92737	-0.8633	0.055988	-0.659	-0.64963	-0.6321	0.015196
50	-0.344	-0.27834	-0.1746	0.062736	-0.9819	-0.9261	-0.764	0.091701	-0.6903	-0.64776	-0.5894	0.043461
60	-0.3047	-0.12128	0.3734	0.28211	-0.9482	-0.78256	-0.318	0.27045	-0.6995	-0.66128	-0.613	0.03852
100	-0.3184	-0.28304	-0.2157	0.041475	-0.4285	-0.3865	-0.3173	0.047087	-0.1349	-0.10346	-0.0433	0.036154
110	-0.306	-0.25256	-0.2082	0.037364	-0.3854	-0.27426	0.0236	0.17064	-0.116	-0.0217	0.2704	0.16464

Device Test: 34.2 EN_VTH_RISING(Enable|RisingThreshold/EN2/7/7///90.9/634//0///@EN_VTH_RISING)





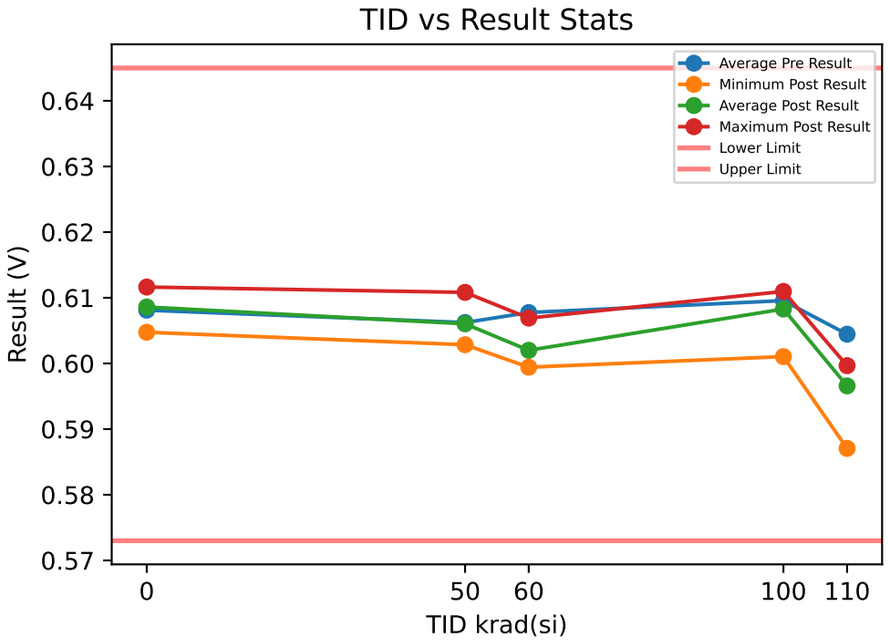
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

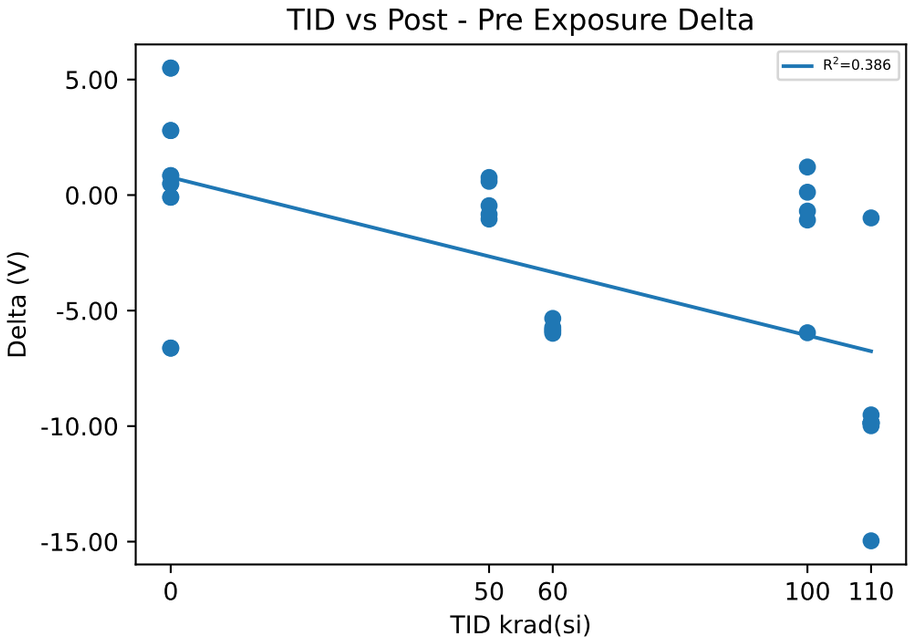
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.60553	0.60525	-0.2773
2	0	CU2	0.60385	0.60378	-0.0623
3	0	CU3	0.60585	0.60662	0.768
11	50	Unbiased-50k	0.60895	0.61103	2.0853
12	50	Unbiased-50k	0.60964	0.60855	-1.0891
13	50	Unbiased-50k	0.60878	0.60776	-1.0185
14	50	Unbiased-50k	0.60202	0.60292	0.8913
16	50	Unbiased-50k	0.61361	0.61191	-1.7063
17	60	Biased-50k	0.61295	0.60778	-5.1742
18	60	Biased-50k	0.61177	0.6064	-5.3672
19	60	Biased-50k	0.60384	0.59683	-7.0091
20	60	Biased-50k	0.60489	0.59874	-6.1408
21	60	Biased-50k	0.6037	0.59782	-5.8827
24	100	Unbiased-100k	0.6117	0.61017	-1.5225
25	100	Unbiased-100k	0.60585	0.60674	0.8925
26	100	Unbiased-100k	0.60474	0.60616	1.4201
27	100	Unbiased-100k	0.60387	0.6026	-1.2705
28	100	Unbiased-100k	0.60463	0.6056	0.9741
29	110	Biased-100k	0.60469	0.5923	-12.384
30	110	Biased-100k	0.61158	0.6027	-8.8862
31	110	Biased-100k	0.60856	0.59969	-8.8734
32	110	Biased-100k	0.61055	0.59673	-13.828
34	110	Biased-100k	0.60055	0.58991	-10.632

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60385	0.60507	0.60585	0.001076	0.60378	0.60522	0.60662	0.0014176	-0.2773	0.1428	0.768	0.55201
50	0.60202	0.6086	0.61361	0.0041714	0.60292	0.60843	0.61191	0.0035266	-1.7063	-0.16746	2.0853	1.592
60	0.6037	0.60743	0.61295	0.0045432	0.59683	0.60151	0.60778	0.0051566	-7.0091	-5.9148	-5.1742	0.72422
100	0.60387	0.60616	0.6117	0.0031765	0.6026	0.60625	0.61017	0.0027109	-1.5225	0.09874	1.4201	1.3825
110	0.60055	0.60719	0.61158	0.0045524	0.58991	0.59627	0.6027	0.0052277	-13.828	-10.921	-8.8734	2.1799

Device Test: 34.3 EN_VTH_RISING(Enable|RisingThreshold/EN3/7/7///90.9/634//0///@EN_VTH_RISING)





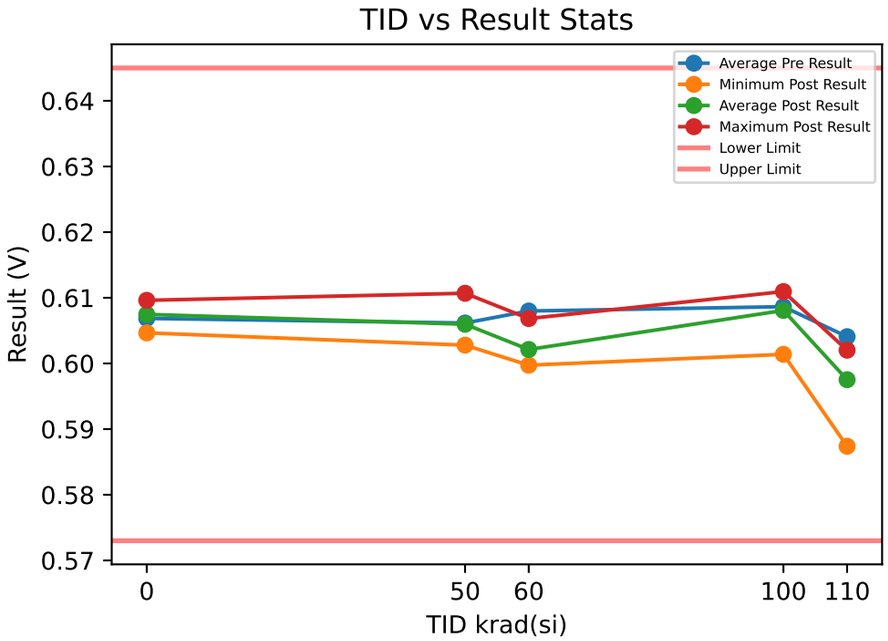
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

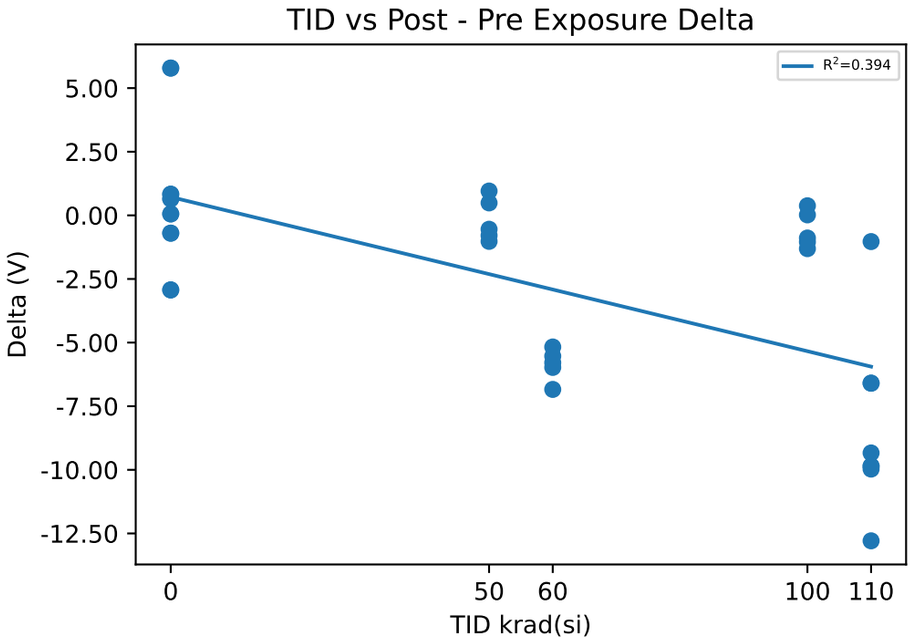
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.61159	0.61149	-0.0919
2	0	CU2	0.60884	0.60933	0.4907
3	0	CU3	0.60391	0.60475	0.841
11	50	Unbiased-50k	0.60398	0.60352	-0.4595
12	50	Unbiased-50k	0.60389	0.60285	-1.0394
13	50	Unbiased-50k	0.61166	0.61082	-0.8331
14	50	Unbiased-50k	0.60883	0.60943	0.5955
16	50	Unbiased-50k	0.6028	0.60356	0.7613
17	60	Biased-50k	0.60576	0.60004	-5.7234
18	60	Biased-50k	0.60477	0.59943	-5.3387
19	60	Biased-50k	0.60593	0.59994	-5.9813
20	60	Biased-50k	0.61273	0.60691	-5.8206
21	60	Biased-50k	0.60958	0.60369	-5.8899
24	100	Unbiased-100k	0.60092	0.60104	0.1234
25	100	Unbiased-100k	0.60974	0.61096	1.2145
26	100	Unbiased-100k	0.61086	0.60978	-1.0796
27	100	Unbiased-100k	0.61166	0.61097	-0.6935
28	100	Unbiased-100k	0.61465	0.60869	-5.9585
29	110	Biased-100k	0.61076	0.59579	-14.965
30	110	Biased-100k	0.59658	0.58706	-9.515
31	110	Biased-100k	0.60585	0.59587	-9.984
32	110	Biased-100k	0.60065	0.59966	-0.9889
34	110	Biased-100k	0.60843	0.59857	-9.8558

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60391	0.60811	0.61159	0.0038912	0.60475	0.60853	0.61149	0.0034449	-0.0919	0.41327	0.841	0.47125
50	0.6028	0.60623	0.61166	0.003825	0.60285	0.60604	0.61082	0.0037753	-1.0394	-0.19504	0.7613	0.82607
60	0.60477	0.60775	0.61273	0.003329	0.59943	0.602	0.60691	0.0032266	-5.9813	-5.7508	-5.3387	0.24896
100	0.60092	0.60957	0.61465	0.0051652	0.60104	0.60829	0.61097	0.0041596	-5.9585	-1.2787	1.2145	2.7597
110	0.59658	0.60445	0.61076	0.0057885	0.58706	0.59539	0.59966	0.0049527	-14.965	-9.0617	-0.9889	5.0423

Device Test: 34.4 EN_VTH_RISING(Enable|RisingThreshold/EN4/7/7///90.9/634//0///@EN_VTH_RISING)





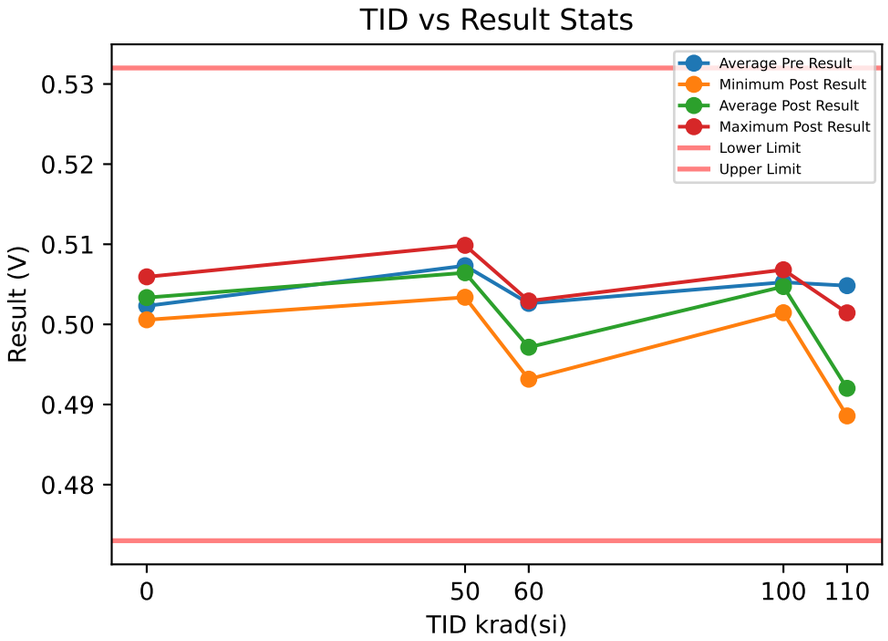
Test Results (Lower Limit = 0.573, Upper Limit = 0.645 (V))

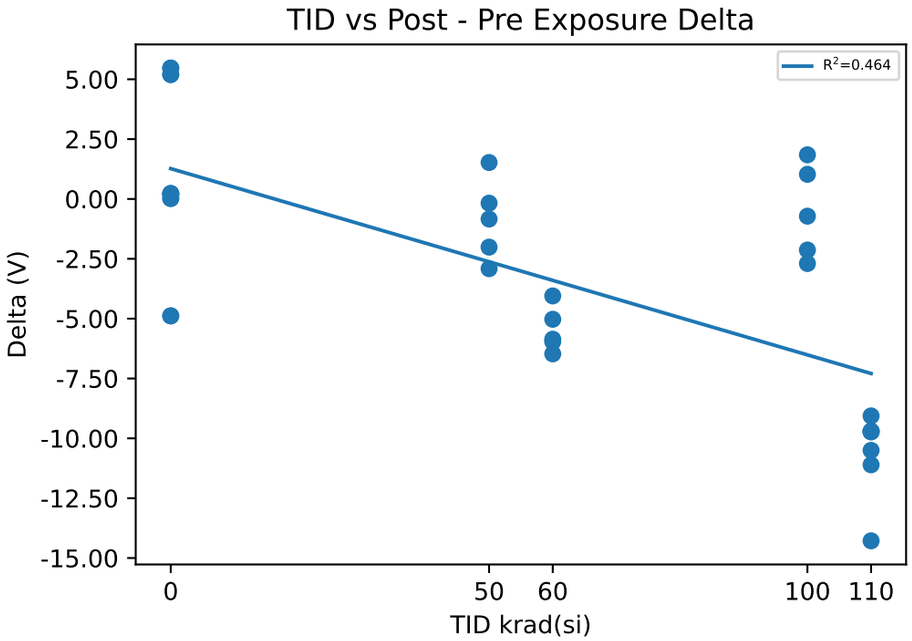
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.60784	0.60789	0.0568
2	0	CU2	0.60892	0.60957	0.6477
3	0	CU3	0.60382	0.60465	0.8305
11	50	Unbiased-50k	0.60393	0.60338	-0.5457
12	50	Unbiased-50k	0.60381	0.60279	-1.0223
13	50	Unbiased-50k	0.61148	0.61069	-0.7911
14	50	Unbiased-50k	0.60876	0.60924	0.4889
16	50	Unbiased-50k	0.60281	0.60376	0.9557
17	60	Biased-50k	0.60587	0.60034	-5.5328
18	60	Biased-50k	0.6049	0.59973	-5.1726
19	60	Biased-50k	0.60582	0.59985	-5.9756
20	60	Biased-50k	0.61263	0.60684	-5.79
21	60	Biased-50k	0.61071	0.60387	-6.8404
24	100	Unbiased-100k	0.60101	0.60138	0.3769
25	100	Unbiased-100k	0.60981	0.60983	0.0186
26	100	Unbiased-100k	0.61069	0.60964	-1.0443
27	100	Unbiased-100k	0.61184	0.61095	-0.8904
28	100	Unbiased-100k	0.60989	0.60858	-1.3086
29	110	Biased-100k	0.60846	0.59567	-12.79
30	110	Biased-100k	0.59672	0.58739	-9.3367
31	110	Biased-100k	0.60577	0.59579	-9.9713
32	110	Biased-100k	0.60081	0.59978	-1.0308
34	110	Biased-100k	0.60862	0.60202	-6.5953

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60382	0.60686	0.60892	0.0026833	0.60465	0.60737	0.60957	0.0024963	0.0568	0.51167	0.8305	0.40439
50	0.60281	0.60616	0.61148	0.0037673	0.60279	0.60597	0.61069	0.003697	-1.0223	-0.1829	0.9557	0.85934
60	0.6049	0.60799	0.61263	0.0034488	0.59973	0.60212	0.60684	0.0031357	-6.8404	-5.8623	-5.1726	0.6243
100	0.60101	0.60865	0.61184	0.0043473	0.60138	0.60808	0.61095	0.0038341	-1.3086	-0.56956	0.3769	0.72736
110	0.59672	0.60408	0.60862	0.0051803	0.58739	0.59613	0.60202	0.0055859	-12.79	-7.9448	-1.0308	4.4481

Device Test: 34.5 EN_VTH_FALLING(Enable|FallingThreshold/EN1/7/7///90.9/634//0///@EN_VTH_FALLING)





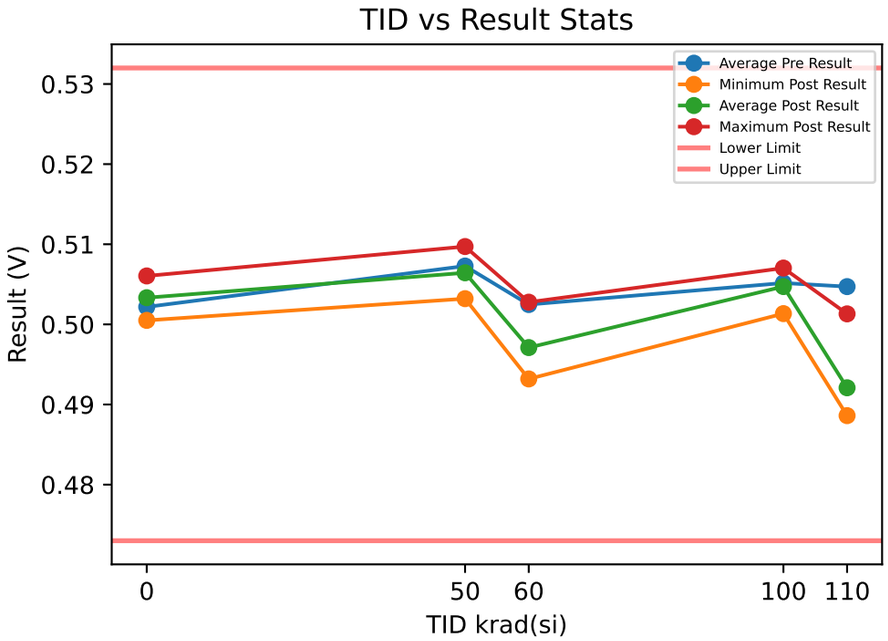
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

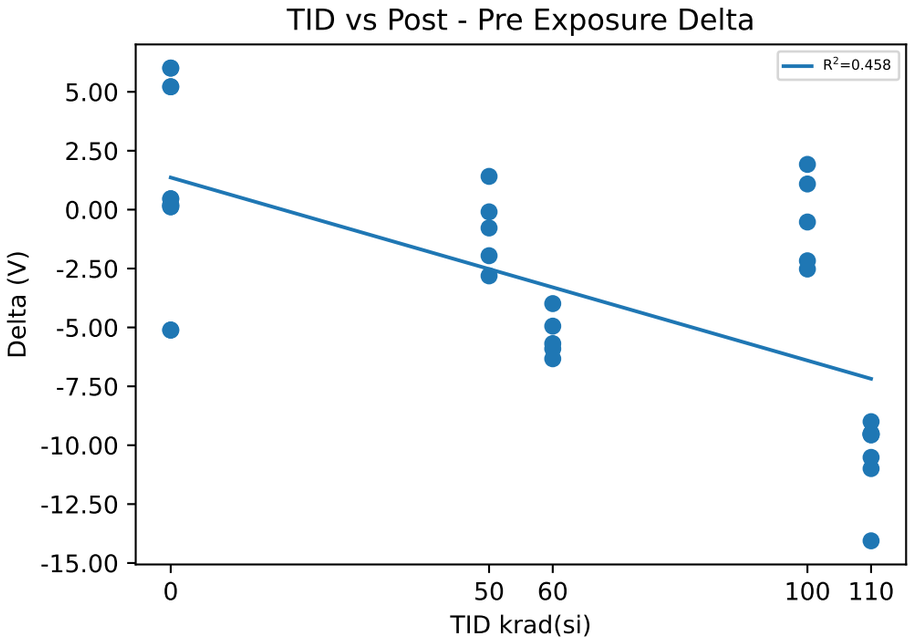
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.50073	0.50096	0.2275
2	0	CU2	0.50581	0.50583	0.0217
3	0	CU3	0.50037	0.50057	0.2027
11	50	Unbiased-50k	0.50562	0.50478	-0.8383
12	50	Unbiased-50k	0.51004	0.50986	-0.1763
13	50	Unbiased-50k	0.50539	0.50338	-2.0123
14	50	Unbiased-50k	0.50395	0.50548	1.5229
16	50	Unbiased-50k	0.51162	0.50871	-2.9128
17	60	Biased-50k	0.50698	0.50292	-4.0513
18	60	Biased-50k	0.50579	0.49983	-5.9629
19	60	Biased-50k	0.49963	0.49316	-6.4706
20	60	Biased-50k	0.50231	0.49645	-5.8594
21	60	Biased-50k	0.49838	0.49336	-5.0267
24	100	Unbiased-100k	0.50705	0.50436	-2.6966
25	100	Unbiased-100k	0.50291	0.50475	1.8441
26	100	Unbiased-100k	0.50754	0.50682	-0.7187
27	100	Unbiased-100k	0.50519	0.50622	1.0303
28	100	Unbiased-100k	0.50359	0.50146	-2.1337
29	110	Biased-100k	0.49968	0.48858	-11.105
30	110	Biased-100k	0.5105	0.50144	-9.0633
31	110	Biased-100k	0.50755	0.49705	-10.501
32	110	Biased-100k	0.50782	0.49354	-14.281
34	110	Biased-100k	0.4986	0.4889	-9.7018

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.50037	0.5023	0.50581	0.0030414	0.50057	0.50245	0.50583	0.0029307	0.0217	0.15063	0.2275	0.11235
50	0.50395	0.50732	0.51162	0.0033109	0.50338	0.50644	0.50986	0.0027351	-2.9128	-0.88336	1.5229	1.7092
60	0.49838	0.50262	0.50698	0.0037429	0.49316	0.49714	0.50292	0.0042232	-6.4706	-5.4742	-4.0513	0.94933
100	0.50291	0.50526	0.50754	0.0020454	0.50146	0.50472	0.50682	0.0020883	-2.6966	-0.53492	1.8441	1.9604
110	0.4986	0.50483	0.5105	0.0053344	0.48858	0.4939	0.50144	0.0054825	-14.281	-10.93	-9.0633	2.0271

Device Test: 34.6 EN_VTH_FALLING(Enable|FallingThreshold/EN2/7/7///90.9/634//0///@EN_VTH_FALLING)





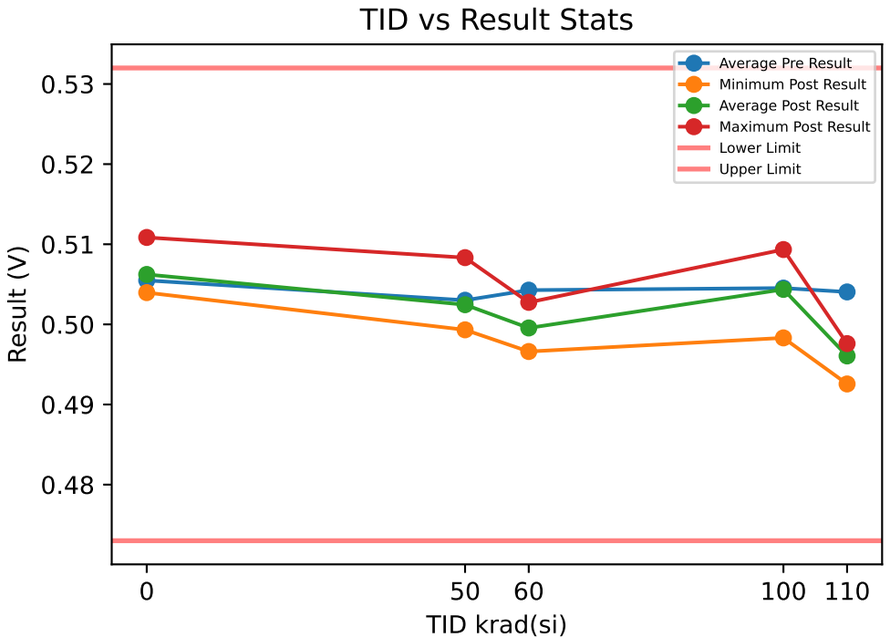
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

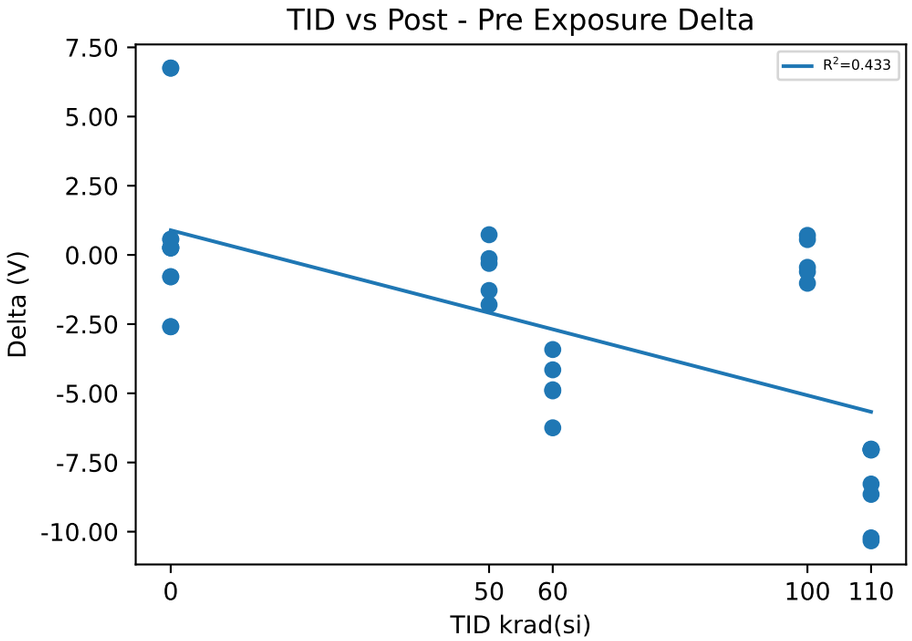
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.5006	0.5008	0.2001
2	0	CU2	0.5059	0.50602	0.1226
3	0	CU3	0.50004	0.5005	0.4604
11	50	Unbiased-50k	0.5057	0.50492	-0.7788
12	50	Unbiased-50k	0.50981	0.50971	-0.0945
13	50	Unbiased-50k	0.50516	0.50321	-1.9558
14	50	Unbiased-50k	0.50411	0.50552	1.4114
16	50	Unbiased-50k	0.51163	0.50882	-2.8113
17	60	Biased-50k	0.50676	0.50277	-3.9891
18	60	Biased-50k	0.50587	0.49997	-5.9054
19	60	Biased-50k	0.49964	0.49331	-6.3302
20	60	Biased-50k	0.50196	0.49628	-5.6858
21	60	Biased-50k	0.49814	0.49319	-4.9455
24	100	Unbiased-100k	0.50676	0.50424	-2.522
25	100	Unbiased-100k	0.5027	0.50462	1.9206
26	100	Unbiased-100k	0.50756	0.50703	-0.5254
27	100	Unbiased-100k	0.50528	0.50637	1.0887
28	100	Unbiased-100k	0.50351	0.50134	-2.1716
29	110	Biased-100k	0.4996	0.48861	-10.992
30	110	Biased-100k	0.51031	0.50131	-9.0006
31	110	Biased-100k	0.50741	0.49689	-10.517
32	110	Biased-100k	0.50763	0.49357	-14.058
34	110	Biased-100k	0.49861	0.4891	-9.5069

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.50004	0.50218	0.5059	0.0032323	0.5005	0.50244	0.50602	0.0031038	0.1226	0.26103	0.4604	0.17695
50	0.50411	0.50728	0.51163	0.0032555	0.50321	0.50644	0.50971	0.0027381	-2.8113	-0.8458	1.4114	1.6401
60	0.49814	0.50248	0.50676	0.0037752	0.49319	0.4971	0.50277	0.0042035	-6.3302	-5.3712	-3.9891	0.92134
100	0.5027	0.50516	0.50756	0.0020664	0.50134	0.50472	0.50703	0.0022189	-2.522	-0.44194	1.9206	1.9525
110	0.49861	0.50471	0.51031	0.0052556	0.48861	0.4939	0.50131	0.0053611	-14.058	-10.815	-9.0006	1.9776

Device Test: 34.7 EN_VTH_FALLING(Enable|FallingThreshold/EN3/7/7///90.9/634//0///@EN_VTH_FALLING)





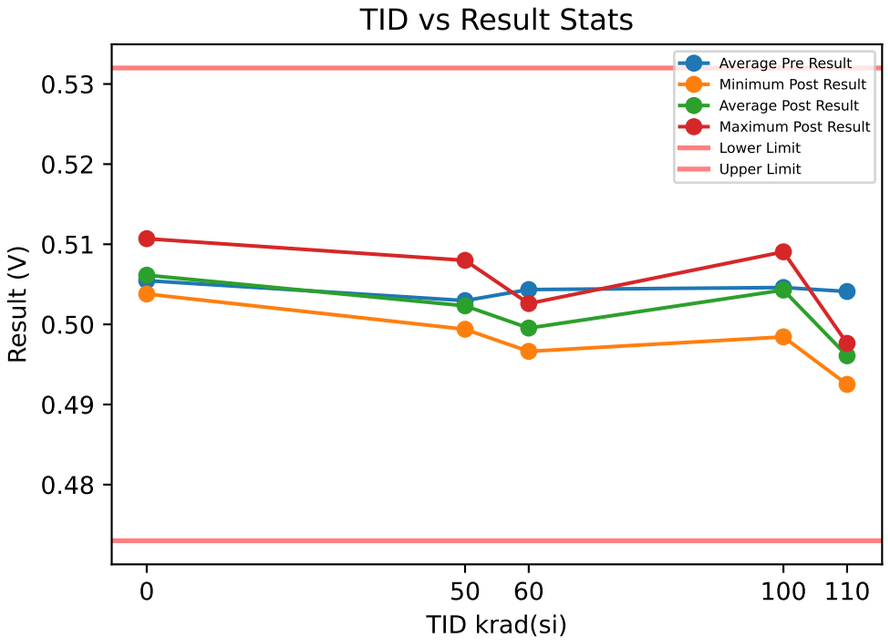
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

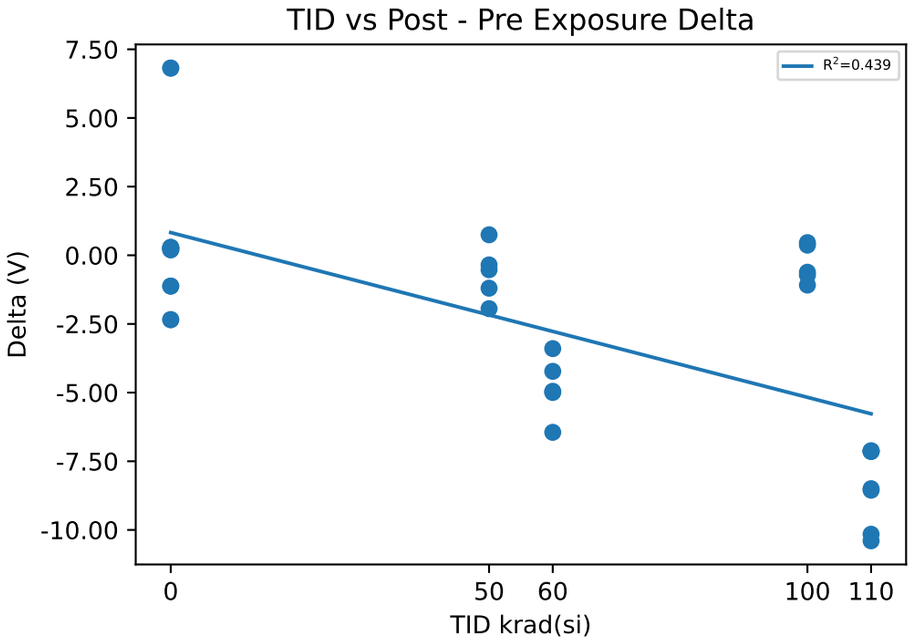
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.5041	0.50435	0.251
2	0	CU2	0.50475	0.50502	0.2706
3	0	CU3	0.50761	0.50818	0.5641
11	50	Unbiased-50k	0.50262	0.50082	-1.7981
12	50	Unbiased-50k	0.50167	0.50137	-0.3059
13	50	Unbiased-50k	0.50372	0.50244	-1.2853
14	50	Unbiased-50k	0.50846	0.50833	-0.1329
16	50	Unbiased-50k	0.49859	0.49932	0.7294
17	60	Biased-50k	0.50152	0.49661	-4.9122
18	60	Biased-50k	0.50298	0.49673	-6.2469
19	60	Biased-50k	0.50565	0.5015	-4.1516
20	60	Biased-50k	0.50762	0.50275	-4.8734
21	60	Biased-50k	0.5036	0.50018	-3.4194
24	100	Unbiased-100k	0.49892	0.49831	-0.6076
25	100	Unbiased-100k	0.50287	0.50358	0.7053
26	100	Unbiased-100k	0.50646	0.50544	-1.0237
27	100	Unbiased-100k	0.5056	0.50515	-0.4488
28	100	Unbiased-100k	0.50879	0.50934	0.5544
29	110	Biased-100k	0.50435	0.49402	-10.33
30	110	Biased-100k	0.50459	0.49594	-8.6516
31	110	Biased-100k	0.50279	0.49256	-10.223
32	110	Biased-100k	0.5039	0.49562	-8.2787
34	110	Biased-100k	0.50462	0.49757	-7.0468

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5041	0.50549	0.50761	0.0018702	0.50435	0.50585	0.50818	0.0020445	0.251	0.3619	0.5641	0.17538
50	0.49859	0.50301	0.50846	0.003595	0.49932	0.50245	0.50833	0.0034706	-1.7981	-0.55856	0.7294	0.99605
60	0.50152	0.50427	0.50762	0.0023862	0.49661	0.49955	0.50275	0.0027824	-6.2469	-4.7207	-3.4194	1.0496
100	0.49892	0.50453	0.50879	0.0037817	0.49831	0.50436	0.50934	0.0039927	-1.0237	-0.16408	0.7053	0.75643
110	0.50279	0.50405	0.50462	0.00076185	0.49256	0.49514	0.49757	0.0019153	-10.33	-8.9061	-7.0468	1.3855

Device Test: 34.8 EN_VTH_FALLING(Enable|FallingThreshold/EN4/7/7///90.9/634//0///@EN_VTH_FALLING)





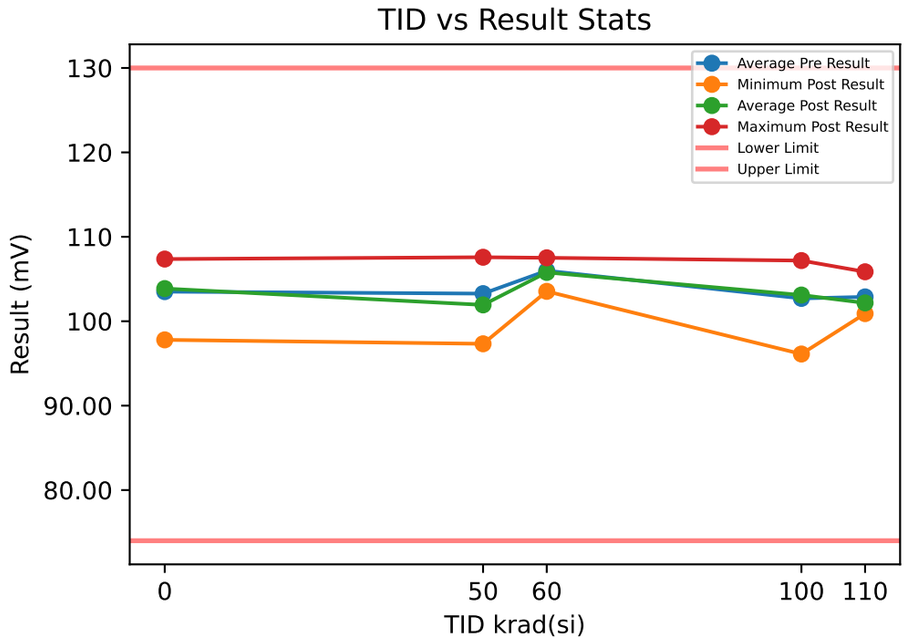
Test Results (Lower Limit = 0.473, Upper Limit = 0.532 (V))

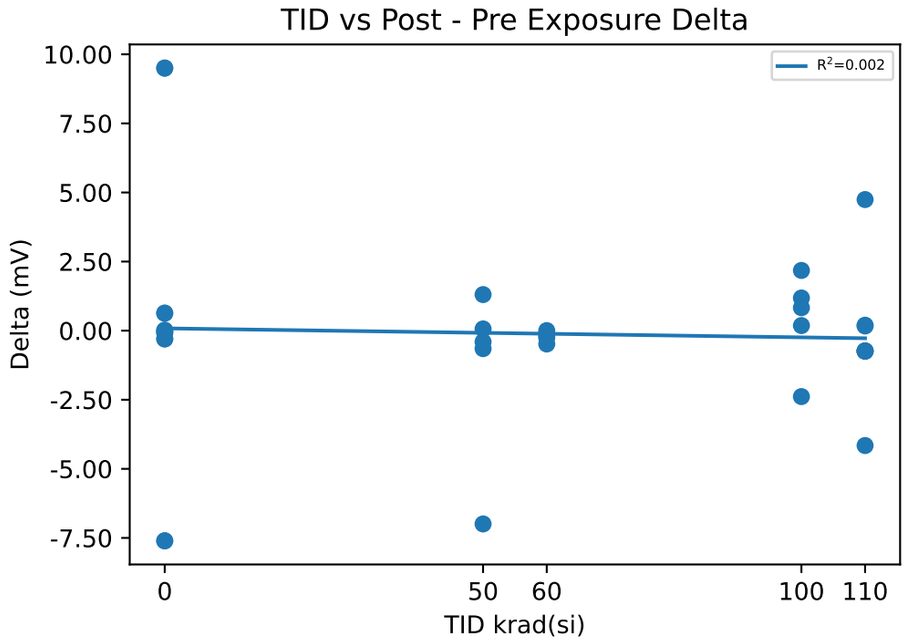
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.50388	0.50408	0.2015
2	0	CU2	0.50492	0.50518	0.2588
3	0	CU3	0.50758	0.50787	0.2881
11	50	Unbiased-50k	0.50259	0.50065	-1.9432
12	50	Unbiased-50k	0.50161	0.50109	-0.5255
13	50	Unbiased-50k	0.50366	0.50246	-1.1983
14	50	Unbiased-50k	0.50834	0.50799	-0.3506
16	50	Unbiased-50k	0.49864	0.49939	0.7465
17	60	Biased-50k	0.50159	0.49663	-4.9522
18	60	Biased-50k	0.50327	0.49682	-6.4463
19	60	Biased-50k	0.50558	0.50135	-4.226
20	60	Biased-50k	0.5076	0.5026	-4.996
21	60	Biased-50k	0.50369	0.5003	-3.3989
24	100	Unbiased-100k	0.49916	0.49844	-0.7245
25	100	Unbiased-100k	0.50307	0.50353	0.4608
26	100	Unbiased-100k	0.50641	0.50532	-1.0854
27	100	Unbiased-100k	0.50568	0.50507	-0.6169
28	100	Unbiased-100k	0.50869	0.50906	0.369
29	110	Biased-100k	0.50421	0.49381	-10.397
30	110	Biased-100k	0.50471	0.49615	-8.5544
31	110	Biased-100k	0.50267	0.49251	-10.157
32	110	Biased-100k	0.50419	0.49569	-8.4989
34	110	Biased-100k	0.50475	0.49761	-7.1426

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.50388	0.50546	0.50758	0.0019098	0.50408	0.50571	0.50787	0.0019499	0.2015	0.24947	0.2881	0.044048
50	0.49864	0.50297	0.50834	0.0035366	0.49939	0.50231	0.50799	0.0033571	-1.9432	-0.65422	0.7465	1.0035
60	0.50159	0.50434	0.5076	0.002307	0.49663	0.49954	0.5026	0.0026956	-6.4463	-4.8039	-3.3989	1.1252
100	0.49916	0.5046	0.50869	0.0036419	0.49844	0.50428	0.50906	0.0038472	-1.0854	-0.3194	0.4608	0.69318
110	0.50267	0.5041	0.50475	0.00084635	0.49251	0.49515	0.49761	0.0020066	-10.397	-8.9499	-7.1426	1.3395

Device Test: 34.9 EN_VTH_HYST(Enable|Hys/EN1/7/7///90.9/634//0///@EN_VTH_HYST)





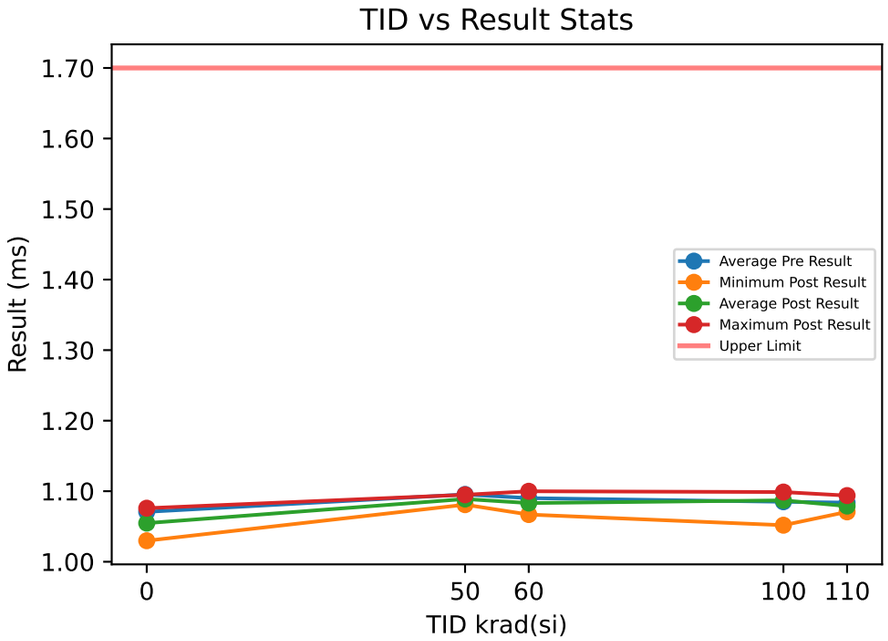
Test Results (Lower Limit = 74.0, Upper Limit = 130.0 (mV))

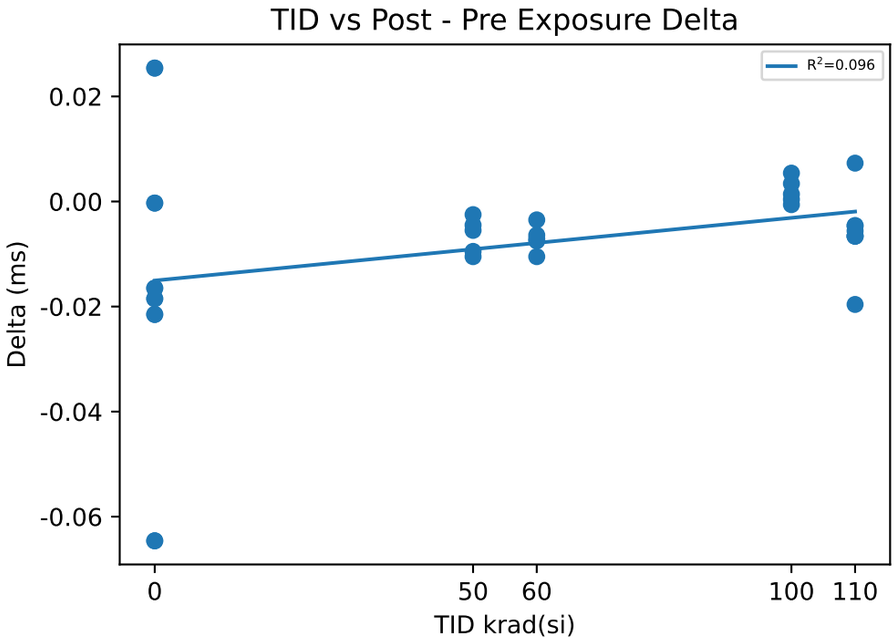
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	107.11	107.12	0.0134
2	0	CU2	97.863	97.794	-0.0693
3	0	CU3	105.54	106.18	0.6328
11	50	Unbiased-50k	103.24	102.83	-0.4035
12	50	Unbiased-50k	105.84	98.85	-6.9938
13	50	Unbiased-50k	107.52	107.58	0.0631
14	50	Unbiased-50k	97.978	97.327	-0.6506
16	50	Unbiased-50k	101.78	103.09	1.3055
17	60	Biased-50k	106.03	105.77	-0.2574
18	60	Biased-50k	105.81	105.62	-0.1828
19	60	Biased-50k	104.02	103.54	-0.4824
20	60	Biased-50k	106.55	106.45	-0.0996
21	60	Biased-50k	107.51	107.51	0.0022
24	100	Unbiased-100k	104.76	105.95	1.1826
25	100	Unbiased-100k	107	107.19	0.1844
26	100	Unbiased-100k	96.955	99.134	2.1792
27	100	Unbiased-100k	98.501	96.116	-2.3855
28	100	Unbiased-100k	106.3	107.13	0.8304
29	110	Biased-100k	107.58	103.43	-4.157
30	110	Biased-100k	101.21	101.41	0.1978
31	110	Biased-100k	101.11	105.86	4.744
32	110	Biased-100k	102.86	103.03	0.1693
34	110	Biased-100k	101.65	100.9	-0.7431

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.863	103.5	107.11	4.9482	97.794	103.7	107.12	5.1342	-0.0693	0.1923	0.6328	0.38372
50	97.978	103.27	107.52	3.704	97.327	101.94	107.58	4.0233	-6.9938	-1.3359	1.3055	3.2513
60	104.02	105.98	107.51	1.279	103.54	105.78	107.51	1.4583	-0.4824	-0.204	0.0022	0.18318
100	96.955	102.7	107	4.6466	96.116	103.1	107.19	5.137	-2.3855	0.39822	2.1792	1.7153
110	101.11	102.88	107.58	2.7177	100.9	102.92	105.86	1.9526	-4.157	0.0422	4.744	3.1779

ce Test: 35.1 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN1/3/3///90.9/634//0///@T_ENABLE_DELAY_





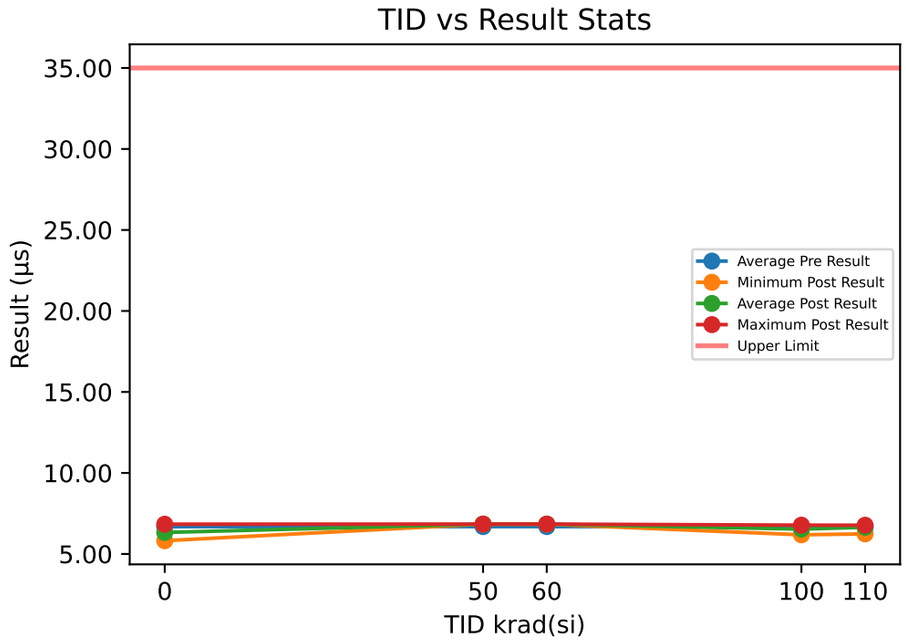
Test Results (Upper Limit = 1.7 (ms))

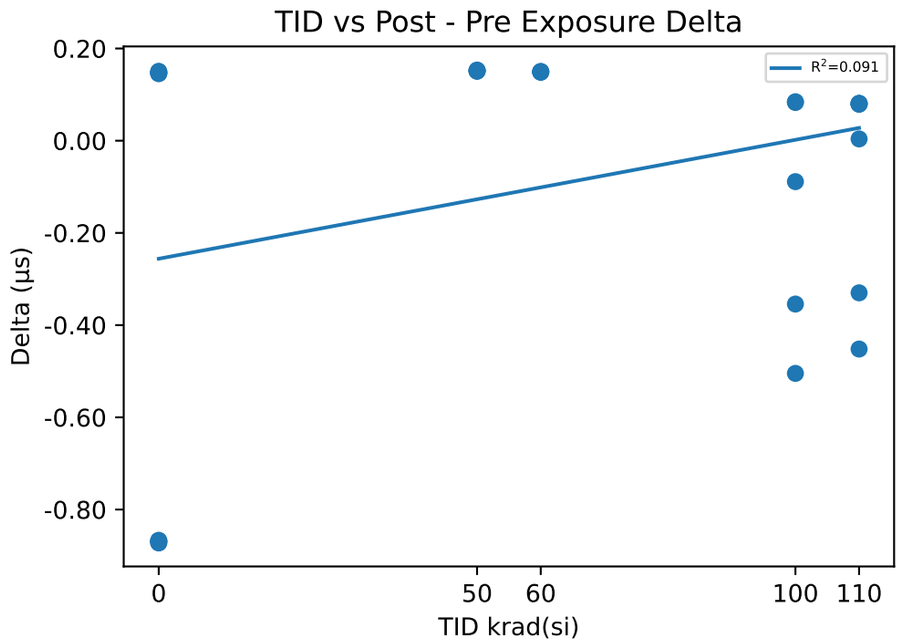
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0494	1.0329	-0.0165
2	0	CU2	1.0944	1.0759	-0.0185
3	0	CU3	1.0684	1.0469	-0.0215
11	50	Unbiased-50k	1.1004	1.0909	-0.0095
12	50	Unbiased-50k	1.0954	1.0849	-0.0105
13	50	Unbiased-50k	1.0974	1.0949	-0.0025
14	50	Unbiased-50k	1.0974	1.0929	-0.0045
16	50	Unbiased-50k	1.0864	1.0809	-0.0055
17	60	Biased-50k	1.0784	1.0713	-0.0071
18	60	Biased-50k	1.1104	1.0999	-0.0105
19	60	Biased-50k	1.0964	1.09	-0.0064
20	60	Biased-50k	1.0914	1.0879	-0.0035
21	60	Biased-50k	1.0744	1.0669	-0.0075
24	100	Unbiased-100k	1.0934	1.0948	0.0014
25	100	Unbiased-100k	1.0934	1.0988	0.0054
26	100	Unbiased-100k	1.0964	1.0968	0.0004
27	100	Unbiased-100k	1.0934	1.0928	-0.0006
28	100	Unbiased-100k	1.0484	1.0518	0.0034
29	110	Biased-100k	1.0634	1.0707	0.0073
30	110	Biased-100k	1.1004	1.0938	-0.0066
31	110	Biased-100k	1.0774	1.0718	-0.0056
32	110	Biased-100k	1.0914	1.0718	-0.0196
34	110	Biased-100k	1.0864	1.0818	-0.0046

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0494	1.0707	1.0944	0.022591	1.0329	1.0519	1.0759	0.021932	-0.0215	-0.018833	-0.0165	0.0025166
50	1.0864	1.0954	1.1004	0.0053385	1.0809	1.0889	1.0949	0.005831	-0.0105	-0.0065	-0.0025	0.0033912
60	1.0744	1.0902	1.1104	0.014464	1.0669	1.0832	1.0999	0.013734	-0.0105	-0.007	-0.0035	0.002506
100	1.0484	1.085	1.0964	0.020501	1.0518	1.087	1.0988	0.019804	-0.0006	0.002	0.0054	0.0024083
110	1.0634	1.0838	1.1004	0.014117	1.0707	1.078	1.0938	0.0099278	-0.0196	-0.00582	0.0073	0.0095416

evice Test: 35.10 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN2/3/3///90.9/634//0///@T_DISABLE_DELA





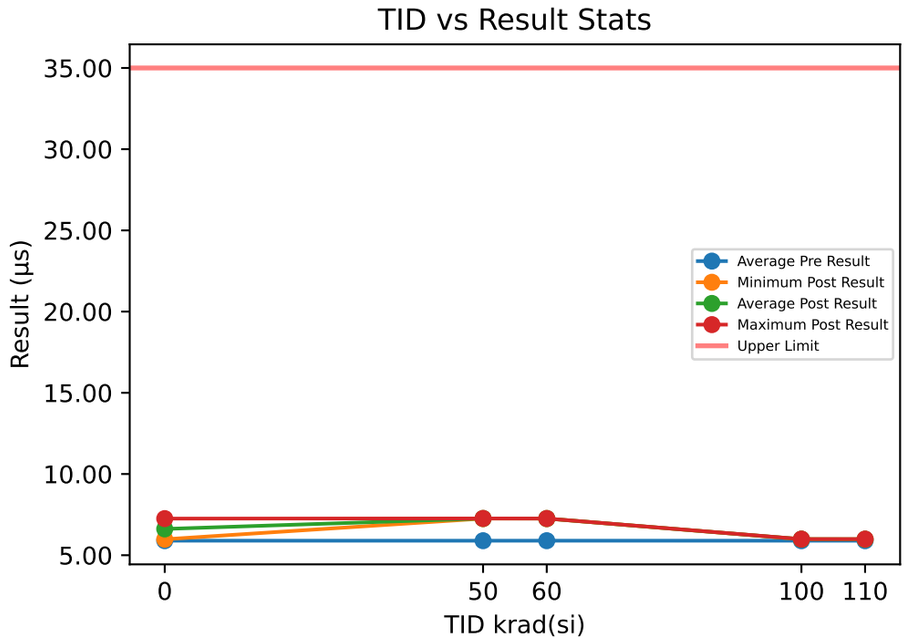
Test Results (Upper Limit = 35.0 (µs))

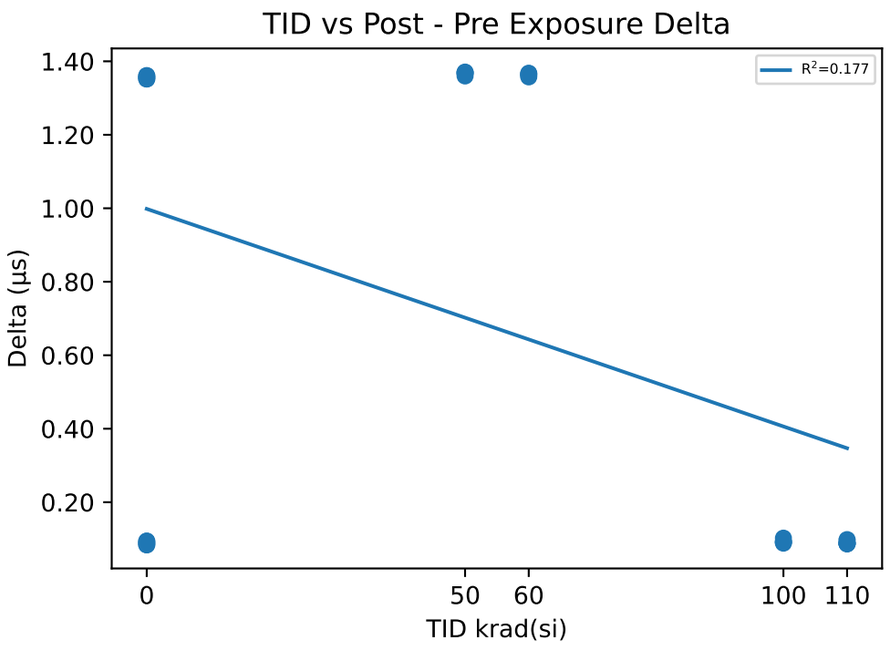
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.6844	6.8345	0.1501
2	0	CU2	6.6883	6.834	0.1457
3	0	CU3	6.6895	6.8368	0.1473
11	50	Unbiased-50k	6.6912	6.8419	0.1507
12	50	Unbiased-50k	6.6891	6.8414	0.1523
13	50	Unbiased-50k	6.6885	6.8417	0.1532
14	50	Unbiased-50k	6.6889	6.8403	0.1514
16	50	Unbiased-50k	6.6901	6.8415	0.1514
17	60	Biased-50k	6.689	6.8374	0.1484
18	60	Biased-50k	6.6889	6.8386	0.1497
19	60	Biased-50k	6.6902	6.8396	0.1494
20	60	Biased-50k	6.6902	6.8395	0.1493
21	60	Biased-50k	6.6925	6.8425	0.15
24	100	Unbiased-100k	6.6887	6.5999	-0.0888
25	100	Unbiased-100k	6.6913	6.7758	0.0845
26	100	Unbiased-100k	6.6882	6.3339	-0.3543
27	100	Unbiased-100k	6.6878	6.1831	-0.5047
28	100	Unbiased-100k	6.6938	6.7767	0.0829
29	110	Biased-100k	6.692	6.7728	0.0808
30	110	Biased-100k	6.6914	6.2395	-0.4519
31	110	Biased-100k	6.6918	6.3618	-0.33
32	110	Biased-100k	6.6896	6.6935	0.0039
34	110	Biased-100k	6.6913	6.7706	0.0793

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6844	6.6874	6.6895	0.0026665	6.834	6.8351	6.8368	0.0014933	0.1457	0.1477	0.1501	0.0022271
50	6.6885	6.6896	6.6912	0.00109	6.8403	6.8414	6.8419	0.0006229	0.1507	0.1518	0.1532	0.00096695
60	6.6889	6.6902	6.6925	0.0014502	6.8374	6.8395	6.8425	0.001886	0.1484	0.14936	0.15	0.00060249
100	6.6878	6.69	6.6938	0.0025442	6.1831	6.5339	6.7767	0.26687	-0.5047	-0.15608	0.0845	0.26474
110	6.6896	6.6912	6.692	0.00094974	6.2395	6.5676	6.7728	0.24958	-0.4519	-0.12358	0.0808	0.24979

evice Test: 35.11 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN3/3/3///90.9/634//0///@T_DISABLE_DELA





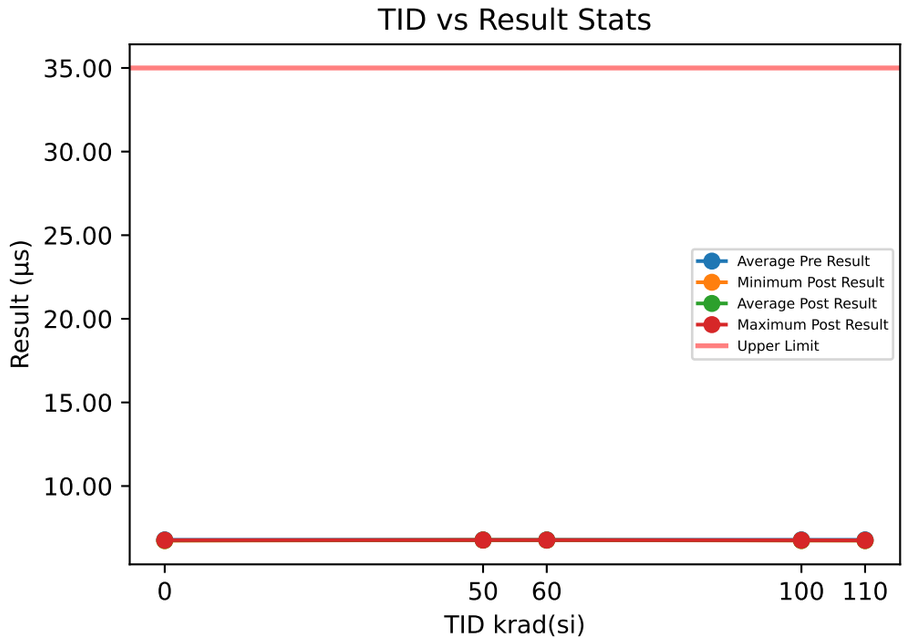
Test Results (Upper Limit = 35.0 (µs))

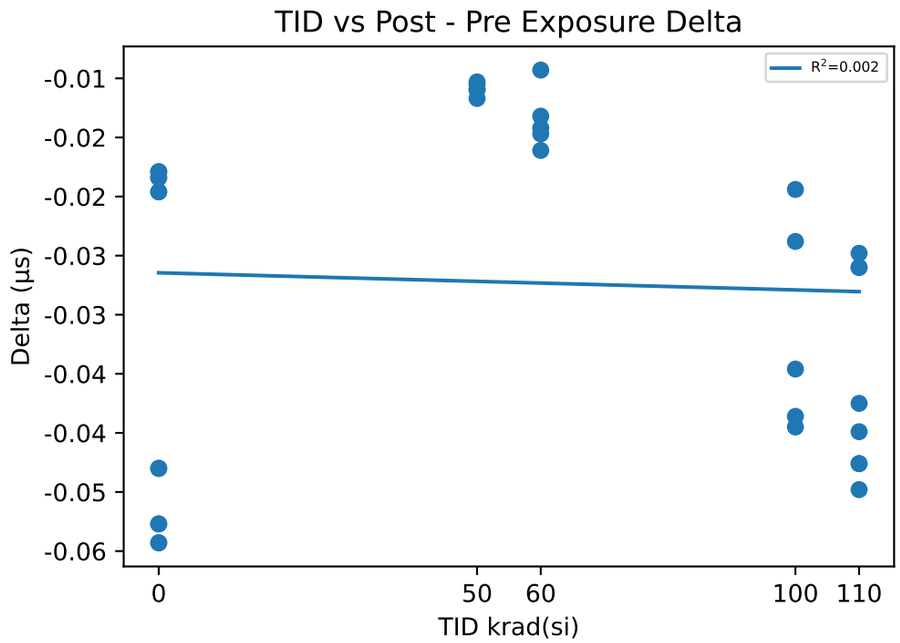
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8937	7.25	1.3563
2	0	CU2	5.8935	7.2544	1.3609
3	0	CU3	5.8979	7.2498	1.3519
11	50	Unbiased-50k	5.8928	7.2621	1.3693
12	50	Unbiased-50k	5.8935	7.2608	1.3673
13	50	Unbiased-50k	5.8928	7.261	1.3682
14	50	Unbiased-50k	5.8957	7.2558	1.3601
16	50	Unbiased-50k	5.8927	7.2634	1.3707
17	60	Biased-50k	5.8925	7.2601	1.3676
18	60	Biased-50k	5.8933	7.2577	1.3644
19	60	Biased-50k	5.8951	7.256	1.3609
20	60	Biased-50k	5.8978	7.2554	1.3576
21	60	Biased-50k	5.8933	7.2594	1.3661
24	100	Unbiased-100k	5.8895	5.9917	0.1022
25	100	Unbiased-100k	5.8948	5.9873	0.0925
26	100	Unbiased-100k	5.8938	5.9863	0.0925
27	100	Unbiased-100k	5.8958	5.9843	0.0885
28	100	Unbiased-100k	5.8965	5.9878	0.0913
29	110	Biased-100k	5.8959	5.9829	0.087
30	110	Biased-100k	5.8949	5.9931	0.0982
31	110	Biased-100k	5.8973	5.9839	0.0866
32	110	Biased-100k	5.8837	5.9802	0.0965
34	110	Biased-100k	5.8931	5.9809	0.0878

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8935	5.895	5.8979	0.0024846	7.2498	7.2514	7.2544	0.0026	1.3519	1.3564	1.3609	0.0045004
50	5.8927	5.8935	5.8957	0.0012708	7.2558	7.2606	7.2634	0.0028865	1.3601	1.3671	1.3707	0.0041246
60	5.8925	5.8944	5.8978	0.002126	7.2554	7.2577	7.2601	0.0020511	1.3576	1.3633	1.3676	0.0040555
100	5.8895	5.8941	5.8965	0.0027563	5.9843	5.9875	5.9917	0.0027133	0.0885	0.0934	0.1022	0.0051836
110	5.8837	5.893	5.8973	0.0054085	5.9802	5.9842	5.9931	0.0051933	0.0866	0.09122	0.0982	0.0056446

evice Test: 35.12 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN4/3/3///90.9/634//0///@T_DISABLE_DELA





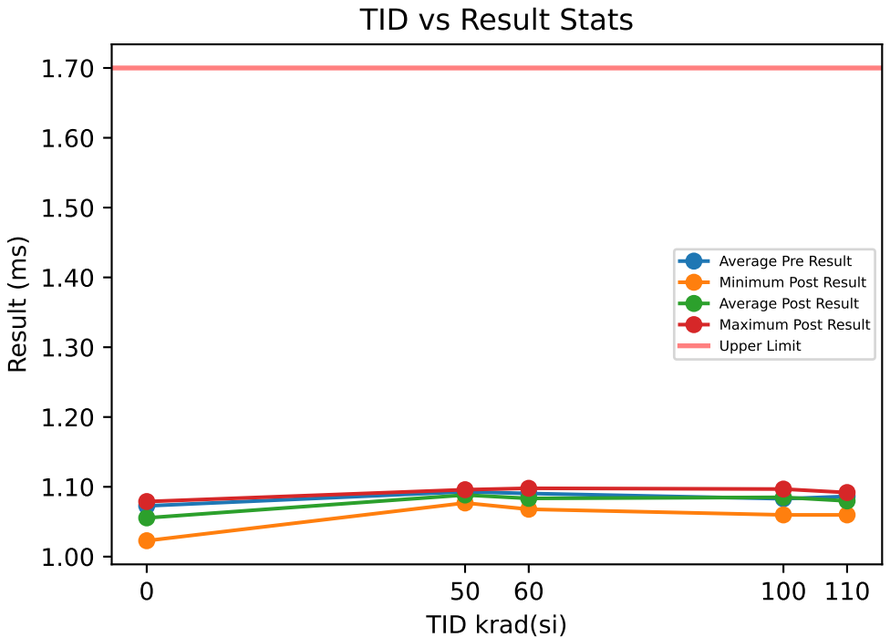
Test Results (Upper Limit = 35.0 (µs))

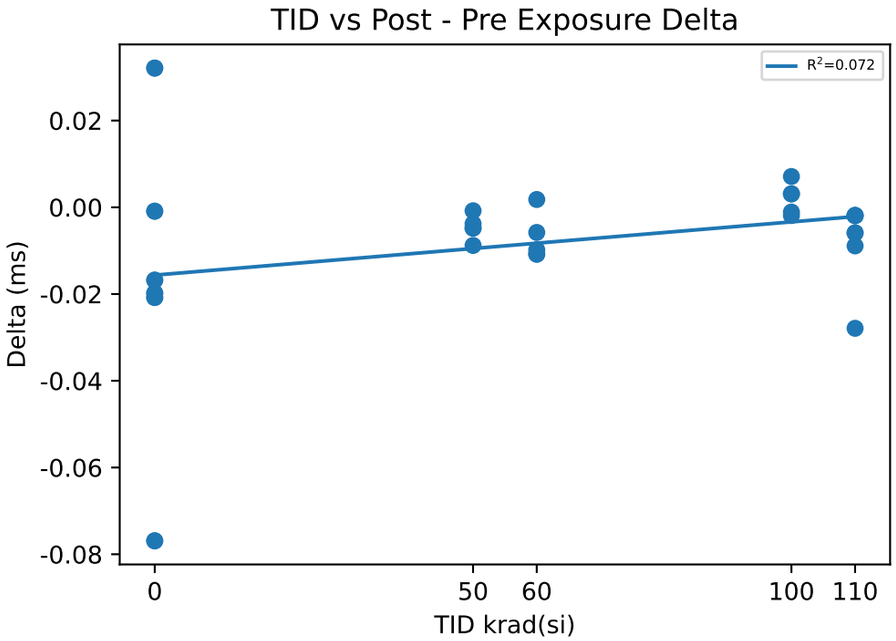
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.7829	6.76	-0.0229
2	0	CU2	6.7831	6.7585	-0.0246
3	0	CU3	6.7855	6.7621	-0.0234
11	50	Unbiased-50k	6.7845	6.7685	-0.016
12	50	Unbiased-50k	6.782	6.7667	-0.0153
13	50	Unbiased-50k	6.7826	6.7659	-0.0167
14	50	Unbiased-50k	6.7836	6.7677	-0.0159
16	50	Unbiased-50k	6.7852	6.7697	-0.0155
17	60	Biased-50k	6.782	6.7677	-0.0143
18	60	Biased-50k	6.7828	6.7646	-0.0182
19	60	Biased-50k	6.7838	6.7646	-0.0192
20	60	Biased-50k	6.7829	6.7632	-0.0197
21	60	Biased-50k	6.7855	6.7644	-0.0211
24	100	Unbiased-100k	6.7836	6.7548	-0.0288
25	100	Unbiased-100k	6.7832	6.7387	-0.0445
26	100	Unbiased-100k	6.7826	6.743	-0.0396
27	100	Unbiased-100k	6.784	6.7596	-0.0244
28	100	Unbiased-100k	6.7854	6.7418	-0.0436
29	110	Biased-100k	6.7845	6.742	-0.0425
30	110	Biased-100k	6.7856	6.7407	-0.0449
31	110	Biased-100k	6.7848	6.735	-0.0498
32	110	Biased-100k	6.7836	6.7538	-0.0298
34	110	Biased-100k	6.7834	6.7524	-0.031

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7829	6.7838	6.7855	0.0014468	6.7585	6.7602	6.7621	0.0018083	-0.0246	-0.023633	-0.0229	0.00087369
50	6.782	6.7836	6.7852	0.0013161	6.7659	6.7677	6.7697	0.00149	-0.0167	-0.01588	-0.0153	0.00054037
60	6.782	6.7834	6.7855	0.001336	6.7632	6.7649	6.7677	0.0016703	-0.0211	-0.0185	-0.0143	0.00257
100	6.7826	6.7838	6.7854	0.0010526	6.7387	6.7476	6.7596	0.0090809	-0.0445	-0.03618	-0.0244	0.009072
110	6.7834	6.7844	6.7856	0.00090111	6.735	6.7448	6.7538	0.0080537	-0.0498	-0.0396	-0.0298	0.0088111

ce Test: 35.2 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN2/3/3///90.9/634//0///@T_ENABLE_DELAY_





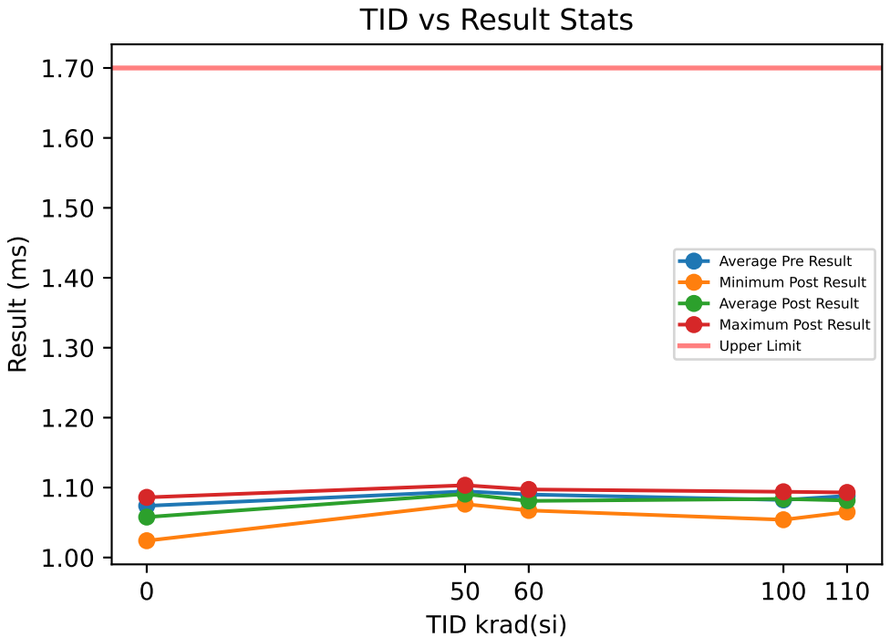
Test Results (Upper Limit = 1.7 (ms))

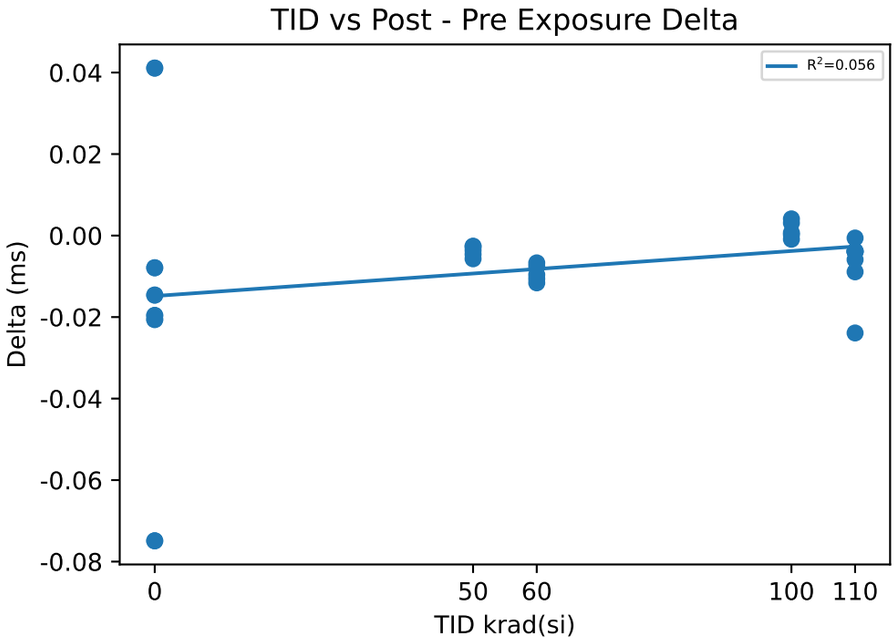
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0437	1.0269	-0.0168
2	0	CU2	1.0997	1.0789	-0.0208
3	0	CU3	1.0747	1.0549	-0.0198
11	50	Unbiased-50k	1.0997	1.0909	-0.0088
12	50	Unbiased-50k	1.0877	1.0829	-0.0048
13	50	Unbiased-50k	1.0967	1.0959	-0.0008
14	50	Unbiased-50k	1.0987	1.0949	-0.0038
16	50	Unbiased-50k	1.0817	1.0769	-0.0048
17	60	Biased-50k	1.0847	1.0789	-0.0058
18	60	Biased-50k	1.1087	1.0979	-0.0108
19	60	Biased-50k	1.0937	1.0839	-0.0098
20	60	Biased-50k	1.0867	1.0885	0.0018
21	60	Biased-50k	1.0787	1.0679	-0.0108
24	100	Unbiased-100k	1.0937	1.0926	-0.0011
25	100	Unbiased-100k	1.0937	1.0968	0.0031
26	100	Unbiased-100k	1.0907	1.0888	-0.0019
27	100	Unbiased-100k	1.0837	1.0868	0.0031
28	100	Unbiased-100k	1.0527	1.0598	0.0071
29	110	Biased-100k	1.0657	1.0598	-0.0059
30	110	Biased-100k	1.1007	1.0918	-0.0089
31	110	Biased-100k	1.0797	1.0738	-0.0059
32	110	Biased-100k	1.0977	1.0698	-0.0279
34	110	Biased-100k	1.0877	1.0858	-0.0019

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0437	1.0727	1.0997	0.028054	1.0269	1.0536	1.0789	0.026026	-0.0208	-0.019133	-0.0168	0.0020817
50	1.0817	1.0929	1.0997	0.0078549	1.0769	1.0883	1.0959	0.0081731	-0.0088	-0.0046	-0.0008	0.0028636
60	1.0787	1.0905	1.1087	0.011498	1.0679	1.0834	1.0979	0.011147	-0.0108	-0.00708	0.0018	0.0053751
100	1.0527	1.0829	1.0937	0.01737	1.0598	1.085	1.0968	0.014575	-0.0019	0.00206	0.0071	0.003648
110	1.0657	1.0863	1.1007	0.014206	1.0598	1.0762	1.0918	0.012759	-0.0279	-0.0101	-0.0019	0.010257

ce Test: 35.3 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN3/3/3///90.9/634//0///@T_ENABLE_DELAY_





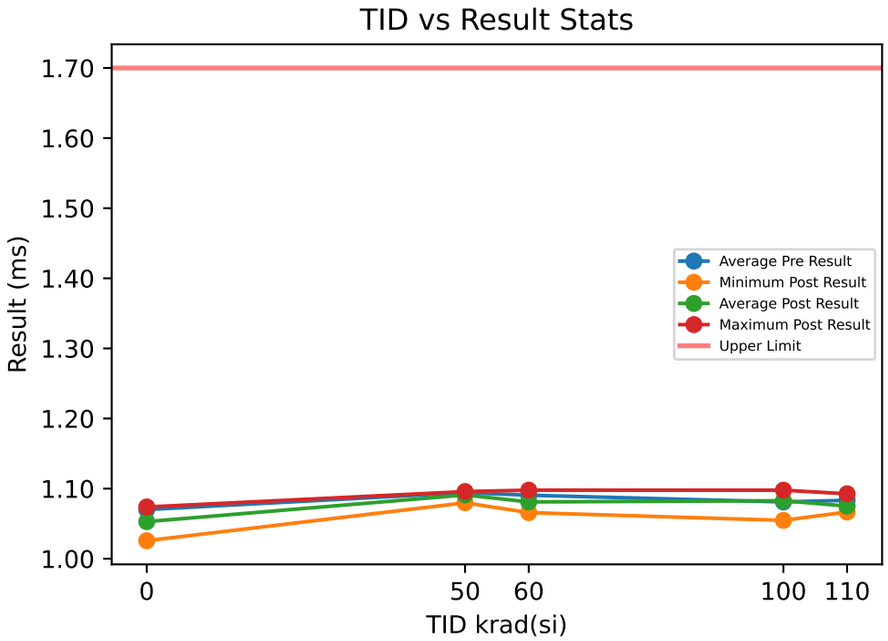
Test Results (Upper Limit = 1.7 (ms))

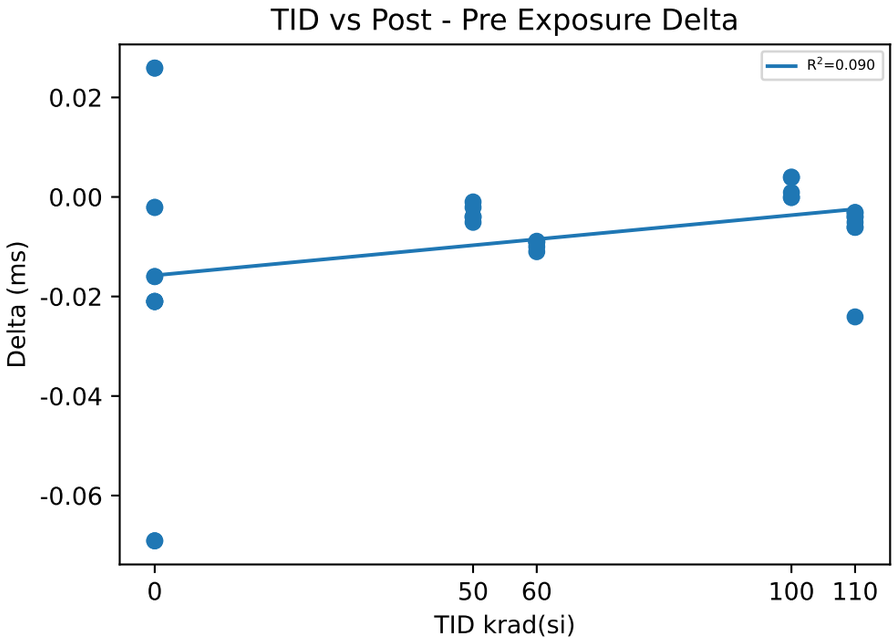
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0449	1.0303	-0.0146
2	0	CU2	1.0989	1.0783	-0.0206
3	0	CU3	1.0779	1.0583	-0.0196
11	50	Unbiased-50k	1.0989	1.0953	-0.0036
12	50	Unbiased-50k	1.084	1.0783	-0.0057
13	50	Unbiased-50k	1.1029	1.1003	-0.0026
14	50	Unbiased-50k	1.106	1.1033	-0.0027
16	50	Unbiased-50k	1.0809	1.0763	-0.0046
17	60	Biased-50k	1.08	1.0733	-0.0067
18	60	Biased-50k	1.1079	1.0973	-0.0106
19	60	Biased-50k	1.0929	1.0833	-0.0096
20	60	Biased-50k	1.0949	1.0833	-0.0116
21	60	Biased-50k	1.0749	1.0673	-0.0076
24	100	Unbiased-100k	1.0949	1.094	-0.0009
25	100	Unbiased-100k	1.0869	1.09	0.0031
26	100	Unbiased-100k	1.0919	1.0926	0.0007
27	100	Unbiased-100k	1.0879	1.0881	0.0002
28	100	Unbiased-100k	1.0499	1.054	0.0041
29	110	Biased-100k	1.0709	1.065	-0.0059
30	110	Biased-100k	1.1019	1.093	-0.0089
31	110	Biased-100k	1.0809	1.0803	-0.0006
32	110	Biased-100k	1.0979	1.074	-0.0239
34	110	Biased-100k	1.0889	1.085	-0.0039

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0449	1.0739	1.0989	0.027221	1.0303	1.0556	1.0783	0.024111	-0.0206	-0.018267	-0.0146	0.0032146
50	1.0809	1.0945	1.106	0.011373	1.0763	1.0907	1.1033	0.012582	-0.0057	-0.00384	-0.0026	0.0013164
60	1.0749	1.0901	1.1079	0.013046	1.0673	1.0809	1.0973	0.011437	-0.0116	-0.00922	-0.0067	0.0020425
100	1.0499	1.0823	1.0949	0.018393	1.054	1.0837	1.094	0.016781	-0.0009	0.00144	0.0041	0.0020852
110	1.0709	1.0881	1.1019	0.012598	1.065	1.0795	1.093	0.010649	-0.0239	-0.00864	-0.0006	0.0090492

ce Test: 35.4 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN4/3/3///90.9/634//0///@T_ENABLE_DELAY_





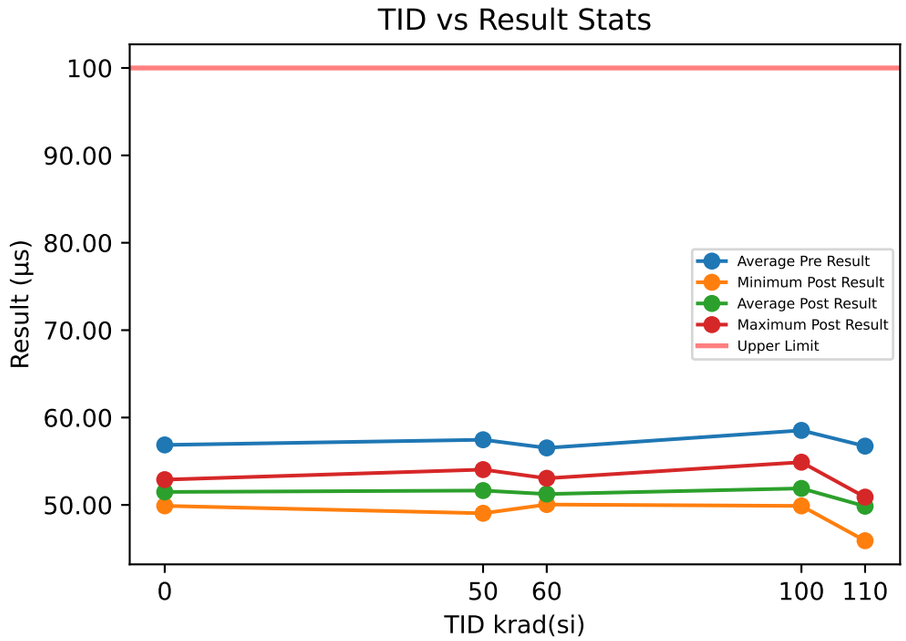
Test Results (Upper Limit = 1.7 (ms))

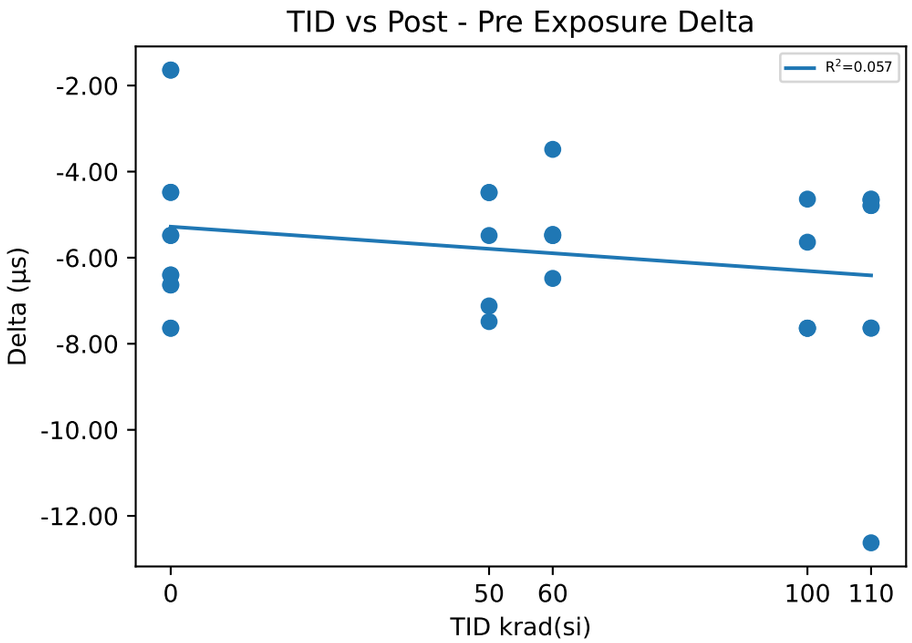
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.0448	1.0288	-0.016
2	0	CU2	1.0948	1.0738	-0.021
3	0	CU3	1.0708	1.0498	-0.021
11	50	Unbiased-50k	1.0958	1.0948	-0.001
12	50	Unbiased-50k	1.0939	1.0888	-0.0051
13	50	Unbiased-50k	1.0979	1.0958	-0.0021
14	50	Unbiased-50k	1.0998	1.0958	-0.004
16	50	Unbiased-50k	1.0838	1.0798	-0.004
17	60	Biased-50k	1.0808	1.0719	-0.0089
18	60	Biased-50k	1.1088	1.0978	-0.011
19	60	Biased-50k	1.0968	1.0878	-0.009
20	60	Biased-50k	1.0918	1.0818	-0.01
21	60	Biased-50k	1.0749	1.0658	-0.0091
24	100	Unbiased-100k	1.0899	1.0898	-0.0001
25	100	Unbiased-100k	1.0938	1.0978	0.004
26	100	Unbiased-100k	1.0858	1.0867	0.0009
27	100	Unbiased-100k	1.0848	1.0847	-0.0001
28	100	Unbiased-100k	1.0508	1.0547	0.0039
29	110	Biased-100k	1.0718	1.0667	-0.0051
30	110	Biased-100k	1.0958	1.0926	-0.0032
31	110	Biased-100k	1.0778	1.0747	-0.0031
32	110	Biased-100k	1.0918	1.0677	-0.0241
34	110	Biased-100k	1.0798	1.0758	-0.004

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0448	1.0701	1.0948	0.025007	1.0288	1.0508	1.0738	0.022517	-0.021	-0.019333	-0.016	0.0028868
50	1.0838	1.0942	1.0998	0.006242	1.0798	1.091	1.0958	0.0069065	-0.0051	-0.00324	-0.001	0.0016532
60	1.0749	1.0906	1.1088	0.013357	1.0658	1.081	1.0978	0.012678	-0.011	-0.0096	-0.0089	0.00089722
100	1.0508	1.081	1.0938	0.017267	1.0547	1.0827	1.0978	0.01645	-0.0001	0.00172	0.004	0.0020765
110	1.0718	1.0834	1.0958	0.01004	1.0667	1.0755	1.0926	0.010385	-0.0241	-0.0079	-0.0031	0.0090915

Device Test: 35.5 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN1/3/3///90.9/634//0///@T_ENABLE_DELAY)





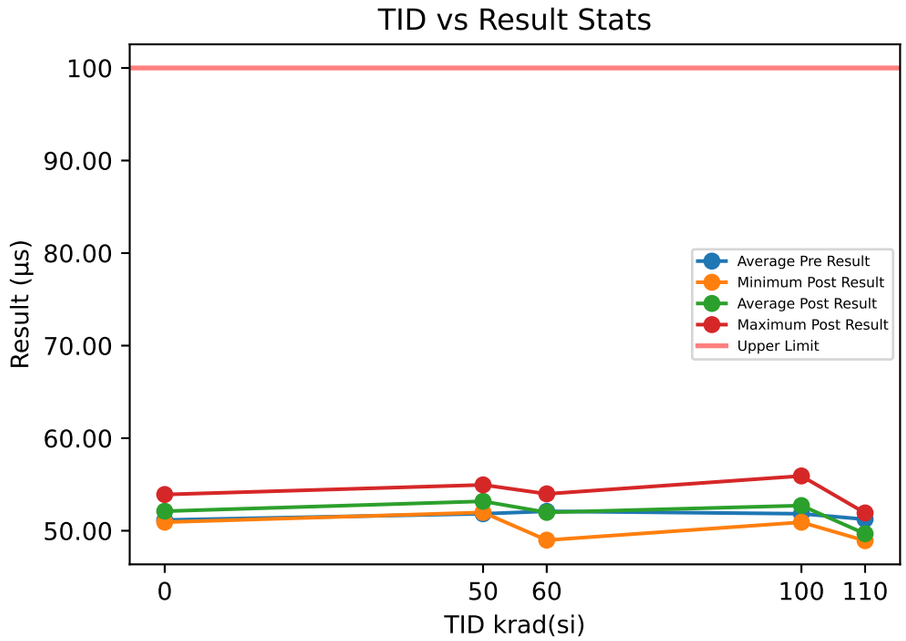
Test Results (Upper Limit = 100.0 (µs))

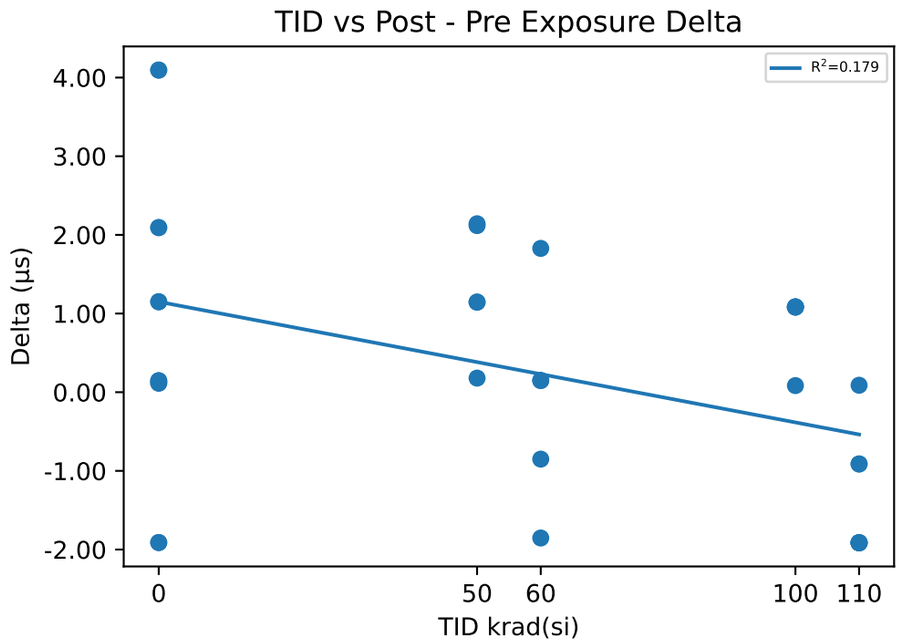
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	54.535	50.053	-4.4819
2	0	CU2	57.533	52.05	-5.4829
3	0	CU3	58.531	52.128	-6.4031
11	50	Unbiased-50k	58.53	54.044	-4.4867
12	50	Unbiased-50k	56.167	49.045	-7.1221
13	50	Unbiased-50k	58.532	53.046	-5.4853
14	50	Unbiased-50k	56.531	49.046	-7.4847
16	50	Unbiased-50k	57.529	53.043	-4.4858
17	60	Biased-50k	56.529	51.045	-5.4839
18	60	Biased-50k	54.531	51.048	-3.4831
19	60	Biased-50k	56.509	51.05	-5.4592
20	60	Biased-50k	55.532	50.047	-5.4845
21	60	Biased-50k	59.53	53.049	-6.4817
24	100	Unbiased-100k	58.531	50.892	-7.6385
25	100	Unbiased-100k	55.531	50.892	-4.6394
26	100	Unbiased-100k	60.53	52.891	-7.6397
27	100	Unbiased-100k	60.531	54.891	-5.6399
28	100	Unbiased-100k	57.527	49.89	-7.6373
29	110	Biased-100k	58.532	50.894	-7.6375
30	110	Biased-100k	55.528	50.891	-4.6375
31	110	Biased-100k	55.531	47.896	-7.6348
32	110	Biased-100k	58.531	45.906	-12.625
34	110	Biased-100k	55.53	50.742	-4.7882

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54.535	56.866	58.531	2.08	50.053	51.41	52.128	1.1763	-6.4031	-5.456	-4.4819	0.96088
50	56.167	57.458	58.532	1.0993	49.045	51.645	54.044	2.4076	-7.4847	-5.8129	-4.4858	1.4262
60	54.531	56.526	59.53	1.8706	50.047	51.248	53.049	1.096	-6.4817	-5.2785	-3.4831	1.0941
100	55.531	58.53	60.531	2.1215	49.89	51.891	54.891	2	-7.6397	-6.639	-4.6394	1.4136
110	55.528	56.73	58.532	1.6439	45.906	49.266	50.894	2.2714	-12.625	-7.4647	-4.6375	3.2345

Device Test: 35.6 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN2/3/3///90.9/634//0///@T_ENABLE_DELAY)





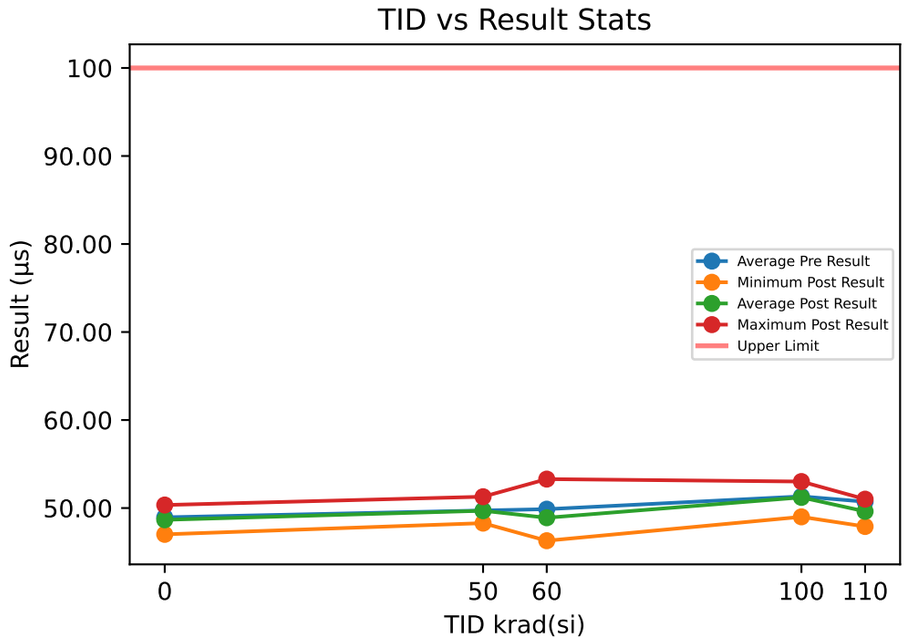
Test Results (Upper Limit = 100.0 (µs))

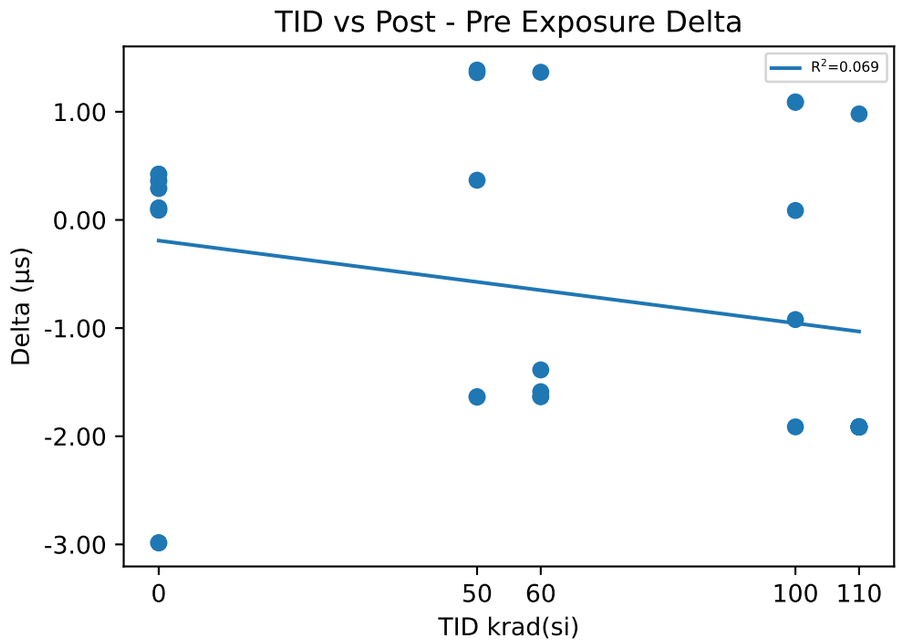
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	49.819	50.969	1.1499
2	0	CU2	52.836	52.982	0.146
3	0	CU3	50.833	50.948	0.1156
11	50	Unbiased-50k	50.835	51.98	1.1446
12	50	Unbiased-50k	52.836	54.954	2.1181
13	50	Unbiased-50k	52.834	53.013	0.1791
14	50	Unbiased-50k	50.832	51.978	1.1454
16	50	Unbiased-50k	51.834	53.975	2.1413
17	60	Biased-50k	53.834	51.98	-1.8537
18	60	Biased-50k	52.155	53.983	1.8281
19	60	Biased-50k	48.835	48.983	0.1484
20	60	Biased-50k	50.834	50.983	0.1487
21	60	Biased-50k	54.833	53.982	-0.8508
24	100	Unbiased-100k	52.839	53.921	1.0819
25	100	Unbiased-100k	50.834	51.919	1.0847
26	100	Unbiased-100k	50.836	50.92	0.084
27	100	Unbiased-100k	54.834	55.919	1.0841
28	100	Unbiased-100k	49.833	50.916	1.0832
29	110	Biased-100k	53.836	51.922	-1.9143
30	110	Biased-100k	49.833	48.921	-0.9123
31	110	Biased-100k	50.837	50.925	0.0885
32	110	Biased-100k	50.837	49.925	-0.9124
34	110	Biased-100k	50.837	48.924	-1.9127

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.819	51.163	52.836	1.535	50.948	51.633	52.982	1.168	0.1156	0.4705	1.1499	0.58857
50	50.832	51.834	52.836	1.0005	51.978	53.18	54.954	1.2934	0.1791	1.3457	2.1413	0.81717
60	48.835	52.098	54.833	2.3844	48.983	51.982	53.983	2.121	-1.8537	-0.11586	1.8281	1.3674
100	49.833	51.835	54.834	2.0007	50.916	52.719	55.919	2.1684	0.084	0.88358	1.0847	0.44698
110	49.833	51.236	53.836	1.5171	48.921	50.123	51.922	1.3039	-1.9143	-1.1126	0.0885	0.83751

Device Test: 35.7 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN3/3/3///90.9/634//0///@T_ENABLE_DELAY)





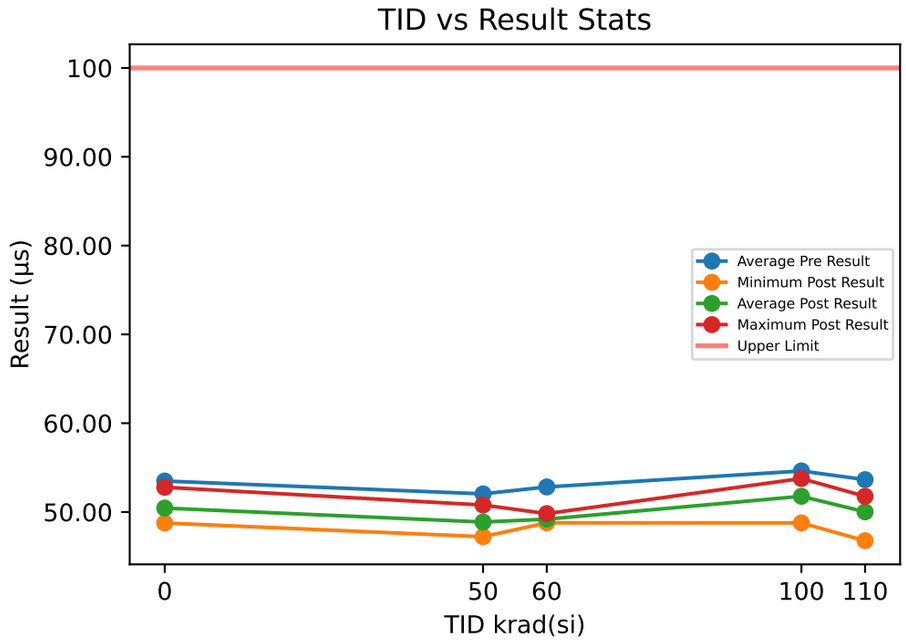
Test Results (Upper Limit = 100.0 (µs))

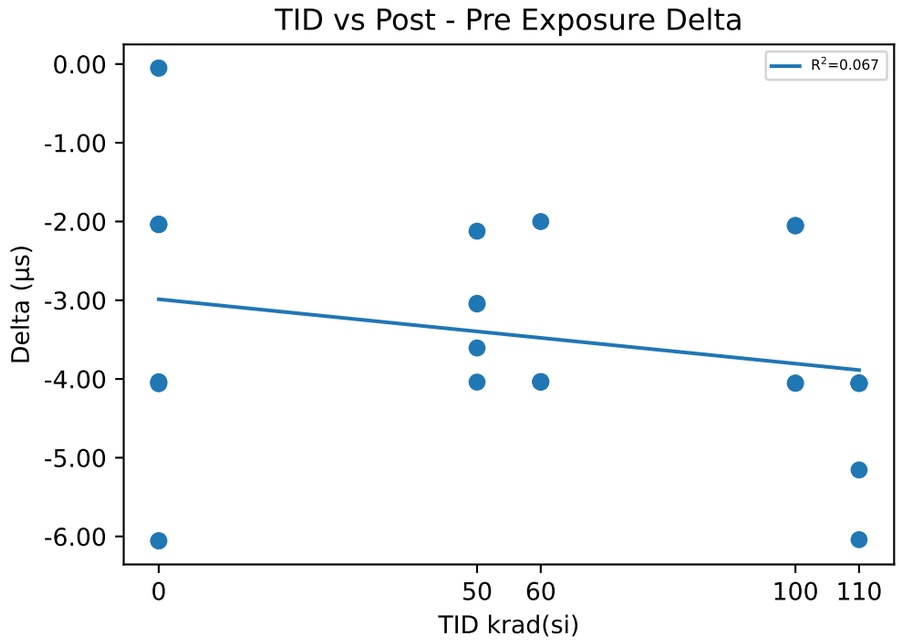
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	46.923	47.286	0.3626
2	0	CU2	49.997	50.289	0.2917
3	0	CU3	49.922	50.345	0.4228
11	50	Unbiased-50k	49.925	48.291	-1.6344
12	50	Unbiased-50k	49.926	51.288	1.362
13	50	Unbiased-50k	49.923	50.29	0.3671
14	50	Unbiased-50k	49.925	48.287	-1.6382
16	50	Unbiased-50k	48.925	50.311	1.3855
17	60	Biased-50k	47.922	46.289	-1.6332
18	60	Biased-50k	51.675	50.288	-1.3866
19	60	Biased-50k	47.924	46.291	-1.6336
20	60	Biased-50k	49.922	48.334	-1.588
21	60	Biased-50k	51.925	53.29	1.3651
24	100	Unbiased-100k	51.922	53.013	1.0907
25	100	Unbiased-100k	49.922	49.001	-0.9212
26	100	Unbiased-100k	51.925	52.013	0.0873
27	100	Unbiased-100k	53.925	52.012	-1.9134
28	100	Unbiased-100k	48.927	50.014	1.0875
29	110	Biased-100k	52.925	51.01	-1.9149
30	110	Biased-100k	46.925	47.905	0.98
31	110	Biased-100k	51.925	50.011	-1.9145
32	110	Biased-100k	49.924	48.013	-1.9108
34	110	Biased-100k	51.925	50.011	-1.9144

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.923	48.948	49.997	1.7535	47.286	49.307	50.345	1.7503	0.2917	0.35903	0.4228	0.065623
50	48.925	49.725	49.926	0.44686	48.287	49.693	51.288	1.344	-1.6382	-0.0316	1.3855	1.5215
60	47.922	49.874	51.925	1.9406	46.289	48.898	53.29	2.9643	-1.6336	-0.97526	1.3651	1.3123
100	48.927	51.324	53.925	1.9492	49.001	51.21	53.013	1.6467	-1.9134	-0.11382	1.0907	1.3062
110	46.925	50.725	52.925	2.3875	47.905	49.39	51.01	1.3689	-1.9149	-1.3349	0.98	1.2941

Device Test: 35.8 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN4/3/3///90.9/634//0///@T_ENABLE_DELAY)





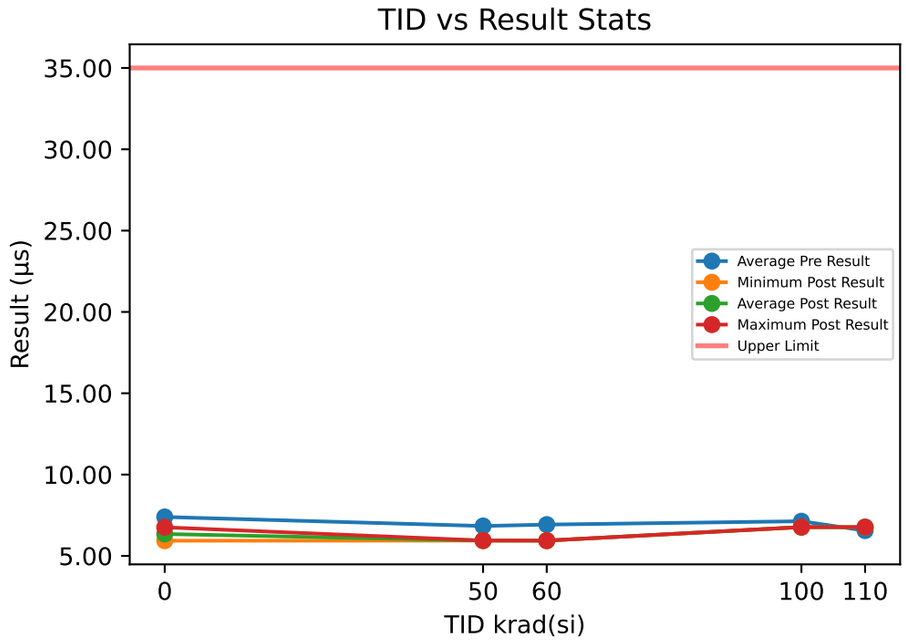
Test Results (Upper Limit = 100.0 (µs))

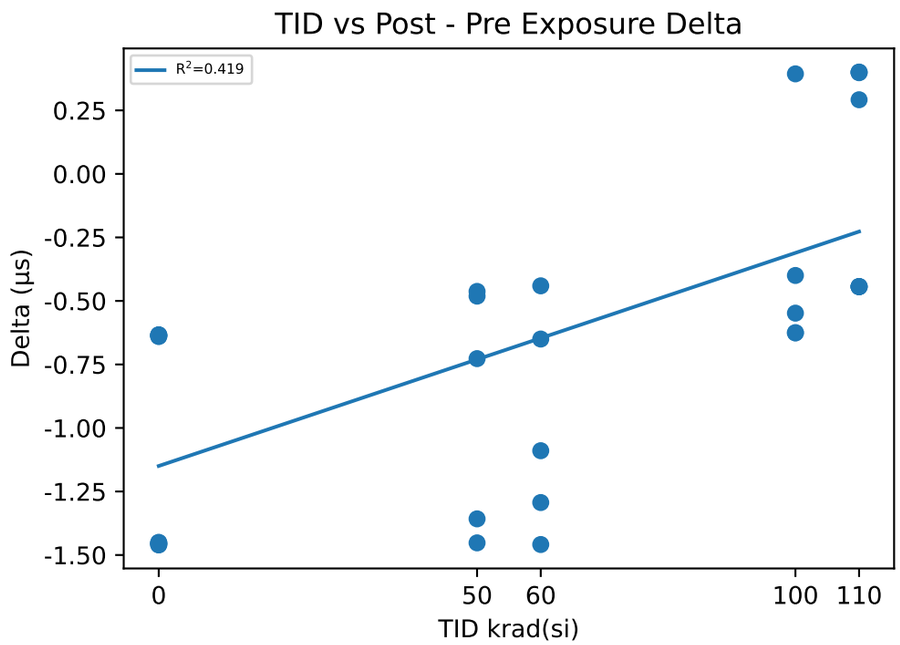
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	52.82	48.782	-4.038
2	0	CU2	54.823	52.784	-2.0389
3	0	CU3	52.819	50.785	-2.0344
11	50	Unbiased-50k	51.907	49.785	-2.1228
12	50	Unbiased-50k	50.822	47.782	-3.0393
13	50	Unbiased-50k	53.833	50.785	-3.0474
14	50	Unbiased-50k	50.823	47.217	-3.6063
16	50	Unbiased-50k	52.822	48.782	-4.0398
17	60	Biased-50k	51.817	49.816	-2.0008
18	60	Biased-50k	52.82	48.782	-4.0377
19	60	Biased-50k	53.819	49.785	-4.0341
20	60	Biased-50k	52.821	48.785	-4.0356
21	60	Biased-50k	52.822	48.782	-4.0393
24	100	Unbiased-100k	52.823	48.769	-4.0532
25	100	Unbiased-100k	55.819	51.765	-4.054
26	100	Unbiased-100k	55.821	53.77	-2.051
27	100	Unbiased-100k	55.824	53.77	-2.0543
28	100	Unbiased-100k	52.823	50.77	-2.0532
29	110	Biased-100k	53.819	49.768	-4.0508
30	110	Biased-100k	50.821	46.766	-4.0547
31	110	Biased-100k	53.923	48.767	-5.1558
32	110	Biased-100k	53.819	47.778	-6.0411
34	110	Biased-100k	55.82	51.766	-4.0544

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.819	53.488	54.823	1.1565	48.782	50.784	52.784	2.0009	-4.038	-2.7038	-2.0344	1.1555
50	50.822	52.041	53.833	1.3047	47.217	48.87	50.785	1.4517	-4.0398	-3.1711	-2.1228	0.72035
60	51.817	52.819	53.819	0.70785	48.782	49.19	49.816	0.55724	-4.0393	-3.6295	-2.0008	0.91047
100	52.823	54.622	55.824	1.6425	48.769	51.769	53.77	2.1216	-4.054	-2.8531	-2.051	1.0959
110	50.821	53.64	55.82	1.792	46.766	48.969	51.766	1.9217	-6.0411	-4.6714	-4.0508	0.90234

Device Test: 35.9 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN1/3/3///90.9/634//0///@T_DISABLE_DELAY





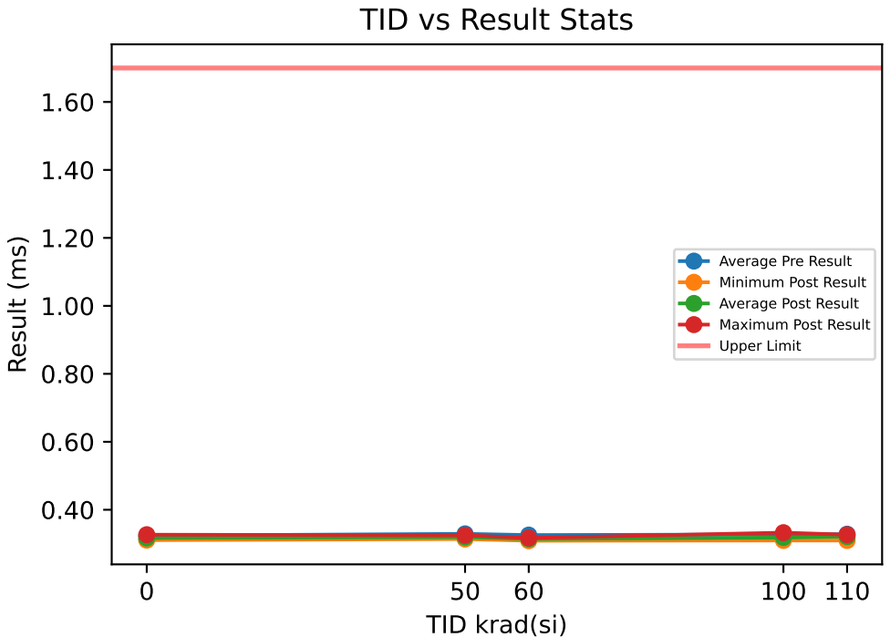
Test Results (Upper Limit = 35.0 (µs))

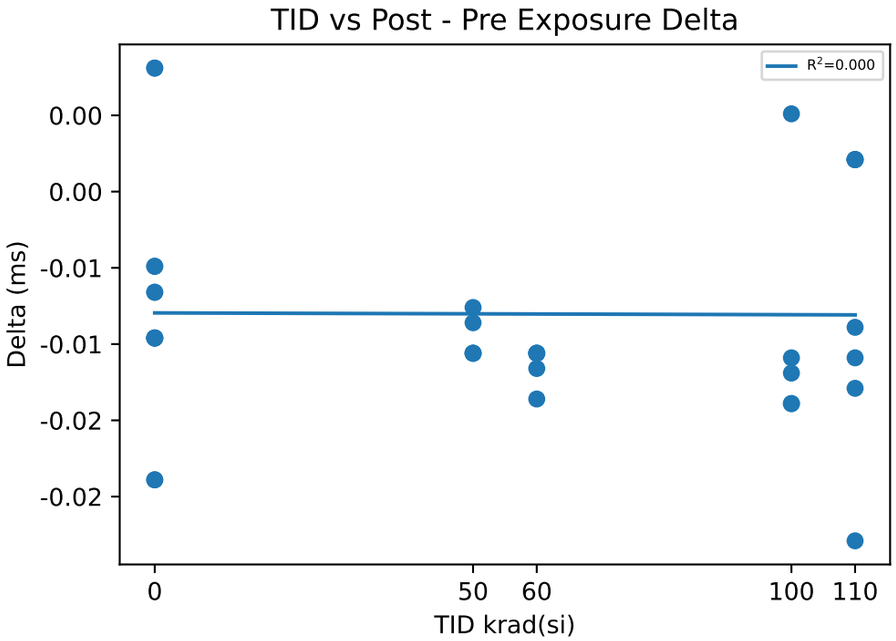
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	7.3973	5.9422	-1.4551
2	0	CU2	7.393	5.9331	-1.4599
3	0	CU3	7.3896	5.9389	-1.4507
11	50	Unbiased-50k	6.6694	5.9423	-0.7271
12	50	Unbiased-50k	6.4026	5.94	-0.4626
13	50	Unbiased-50k	6.4209	5.9398	-0.4811
14	50	Unbiased-50k	7.3983	5.9461	-1.4522
16	50	Unbiased-50k	7.2993	5.9416	-1.3577
17	60	Biased-50k	6.379	5.9384	-0.4406
18	60	Biased-50k	7.2324	5.9389	-1.2935
19	60	Biased-50k	7.0278	5.9383	-1.0895
20	60	Biased-50k	7.3964	5.9377	-1.4587
21	60	Biased-50k	6.5893	5.9393	-0.65
24	100	Unbiased-100k	6.3744	6.7681	0.3937
25	100	Unbiased-100k	7.3943	6.7683	-0.626
26	100	Unbiased-100k	7.1699	6.7701	-0.3998
27	100	Unbiased-100k	7.3957	6.7709	-0.6248
28	100	Unbiased-100k	7.3202	6.7721	-0.5481
29	110	Biased-100k	6.4765	6.7683	0.2918
30	110	Biased-100k	6.3666	6.7664	0.3998
31	110	Biased-100k	6.3644	6.7627	0.3983
32	110	Biased-100k	6.3643	6.765	0.4007
34	110	Biased-100k	7.2101	6.7664	-0.4437

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.3896	7.3933	7.3973	0.0038588	5.9331	5.9381	5.9422	0.0046069	-1.4599	-1.4552	-1.4507	0.0046014
50	6.4026	6.8381	7.3983	0.47925	5.9398	5.942	5.9461	0.0025442	-1.4522	-0.89614	-0.4626	0.47724
60	6.379	6.925	7.3964	0.42956	5.9377	5.9385	5.9393	0.00060992	-1.4587	-0.98646	-0.4406	0.42985
100	6.3744	7.1309	7.3957	0.43277	6.7681	6.7699	6.7721	0.0017088	-0.626	-0.361	0.3937	0.43183
110	6.3643	6.5564	7.2101	0.36861	6.7627	6.7658	6.7683	0.0020744	-0.4437	0.20938	0.4007	0.36806

ce Test: 36.1 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN1/7/7///90.9/634//0///@T_ENABLE_DELAY_





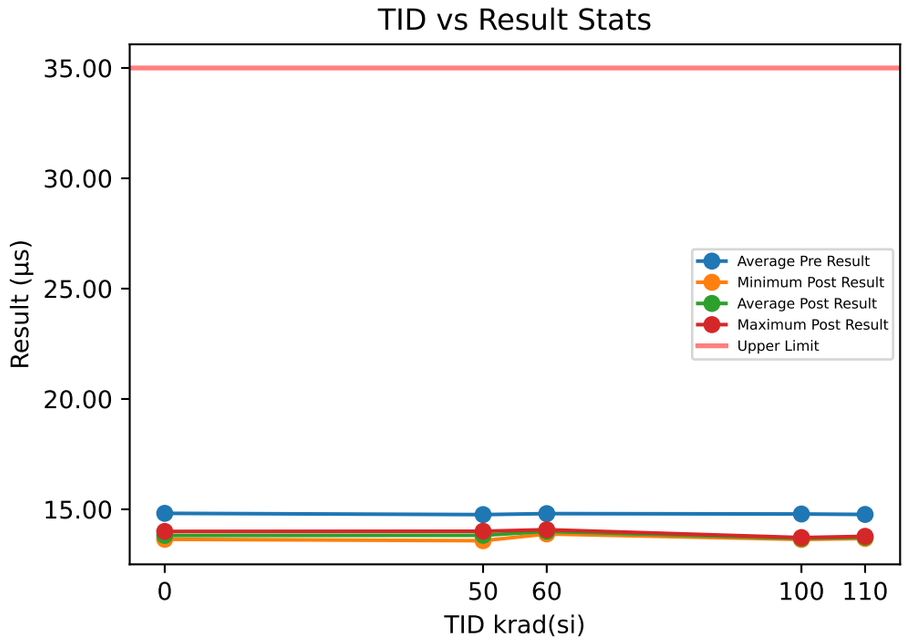
Test Results (Upper Limit = 1.7 (ms))

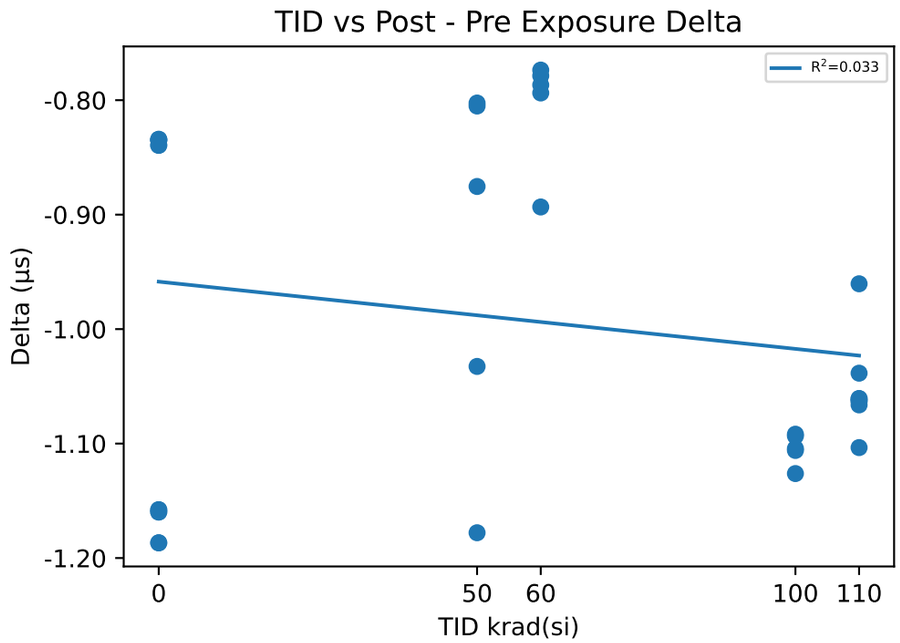
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3185	0.3119	-0.0066
2	0	CU2	0.3295	0.3199	-0.0096
3	0	CU3	0.3235	0.3139	-0.0096
11	50	Unbiased-50k	0.3355	0.3249	-0.0106
12	50	Unbiased-50k	0.3245	0.3139	-0.0106
13	50	Unbiased-50k	0.3275	0.3169	-0.0106
14	50	Unbiased-50k	0.3275	0.3189	-0.0086
16	50	Unbiased-50k	0.3305	0.3229	-0.0076
17	60	Biased-50k	0.3265	0.3159	-0.0106
18	60	Biased-50k	0.3245	0.3129	-0.0116
19	60	Biased-50k	0.3275	0.3169	-0.0106
20	60	Biased-50k	0.3295	0.3159	-0.0136
21	60	Biased-50k	0.3195	0.3089	-0.0106
24	100	Unbiased-100k	0.3335	0.3196	-0.0139
25	100	Unbiased-100k	0.3275	0.3326	0.0051
26	100	Unbiased-100k	0.3275	0.3136	-0.0139
27	100	Unbiased-100k	0.3275	0.3156	-0.0119
28	100	Unbiased-100k	0.3205	0.3096	-0.0109
29	110	Biased-100k	0.3235	0.3106	-0.0129
30	110	Biased-100k	0.3285	0.3196	-0.0089
31	110	Biased-100k	0.3315	0.3206	-0.0109
32	110	Biased-100k	0.3325	0.3096	-0.0229
34	110	Biased-100k	0.3245	0.3266	0.0021

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3185	0.32383	0.3295	0.0055076	0.3119	0.31523	0.3199	0.0041633	-0.0096	-0.0086	-0.0066	0.0017321
50	0.3245	0.3291	0.3355	0.0041593	0.3139	0.3195	0.3249	0.0044497	-0.0106	-0.0096	-0.0076	0.0014142
60	0.3195	0.3255	0.3295	0.0038079	0.3089	0.3141	0.3169	0.0032711	-0.0136	-0.0114	-0.0106	0.0013038
100	0.3205	0.3273	0.3335	0.0046043	0.3096	0.3182	0.3326	0.0088204	-0.0139	-0.0091	0.0051	0.0080436
110	0.3235	0.3281	0.3325	0.0040373	0.3096	0.3174	0.3266	0.0071903	-0.0229	-0.0107	0.0021	0.0089554

evice Test: 36.10 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN2/7/7///90.9/634//0///@T_DISABLE_DELA





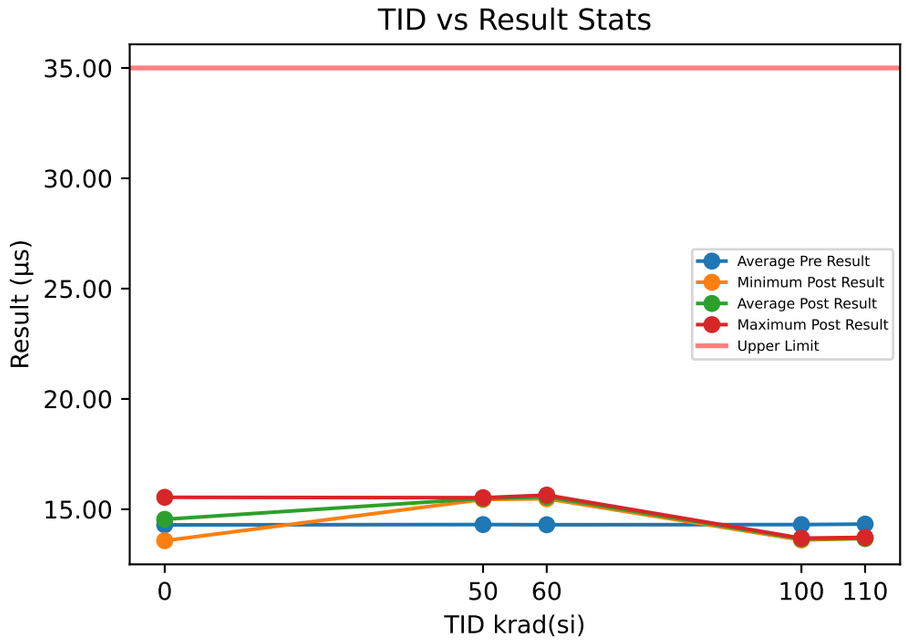
Test Results (Upper Limit = 35.0 (µs))

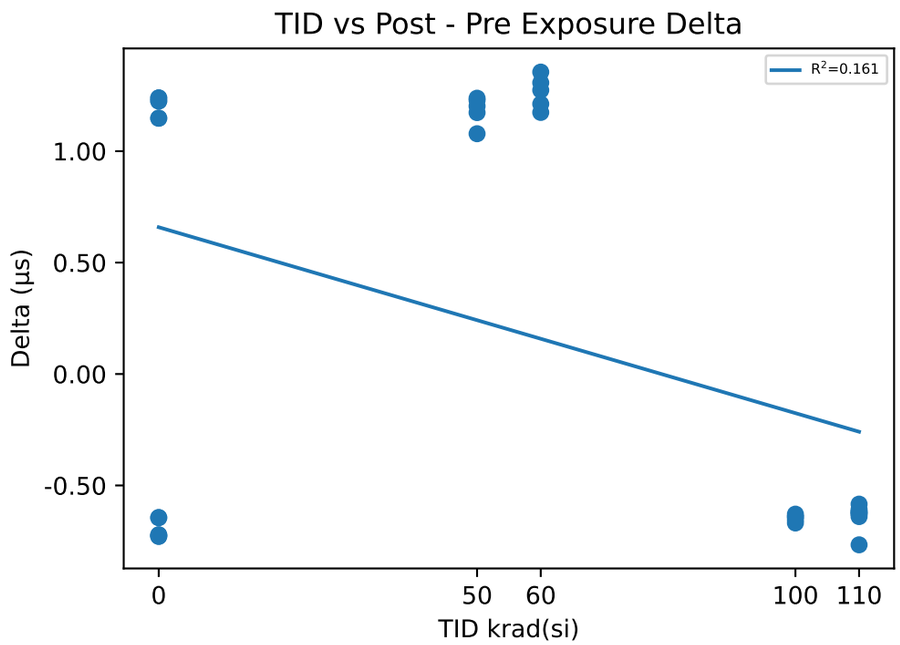
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	14.821	13.982	-0.8394
2	0	CU2	14.798	13.963	-0.835
3	0	CU3	14.831	13.997	-0.8342
11	50	Unbiased-50k	14.808	14.005	-0.8025
12	50	Unbiased-50k	14.656	13.624	-1.0326
13	50	Unbiased-50k	14.808	13.933	-0.8754
14	50	Unbiased-50k	14.772	13.966	-0.8051
16	50	Unbiased-50k	14.754	13.576	-1.1779
17	60	Biased-50k	14.775	13.882	-0.8933
18	60	Biased-50k	14.792	14.018	-0.7737
19	60	Biased-50k	14.788	14.001	-0.7867
20	60	Biased-50k	14.811	14.017	-0.7937
21	60	Biased-50k	14.854	14.075	-0.7787
24	100	Unbiased-100k	14.787	13.695	-1.0918
25	100	Unbiased-100k	14.814	13.708	-1.106
26	100	Unbiased-100k	14.76	13.634	-1.1262
27	100	Unbiased-100k	14.762	13.658	-1.1043
28	100	Unbiased-100k	14.812	13.719	-1.0934
29	110	Biased-100k	14.813	13.775	-1.0385
30	110	Biased-100k	14.638	13.678	-0.9604
31	110	Biased-100k	14.784	13.681	-1.1035
32	110	Biased-100k	14.776	13.71	-1.0662
34	110	Biased-100k	14.822	13.759	-1.0627

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.798	14.817	14.831	0.017169	13.963	13.98	13.997	0.017143	-0.8394	-0.8362	-0.8342	0.0028
50	14.656	14.76	14.808	0.062274	13.576	13.821	14.005	0.20402	-1.1779	-0.9387	-0.8025	0.16313
60	14.775	14.804	14.854	0.030498	13.882	13.999	14.075	0.070894	-0.8933	-0.80522	-0.7737	0.049826
100	14.76	14.787	14.814	0.025994	13.634	13.683	13.719	0.035619	-1.1262	-1.1043	-1.0918	0.013762
110	14.638	14.767	14.822	0.074287	13.678	13.72	13.775	0.044511	-1.1035	-1.0463	-0.9604	0.05333

evice Test: 36.11 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN3/7/7///90.9/634//0///@T_DISABLE_DELA





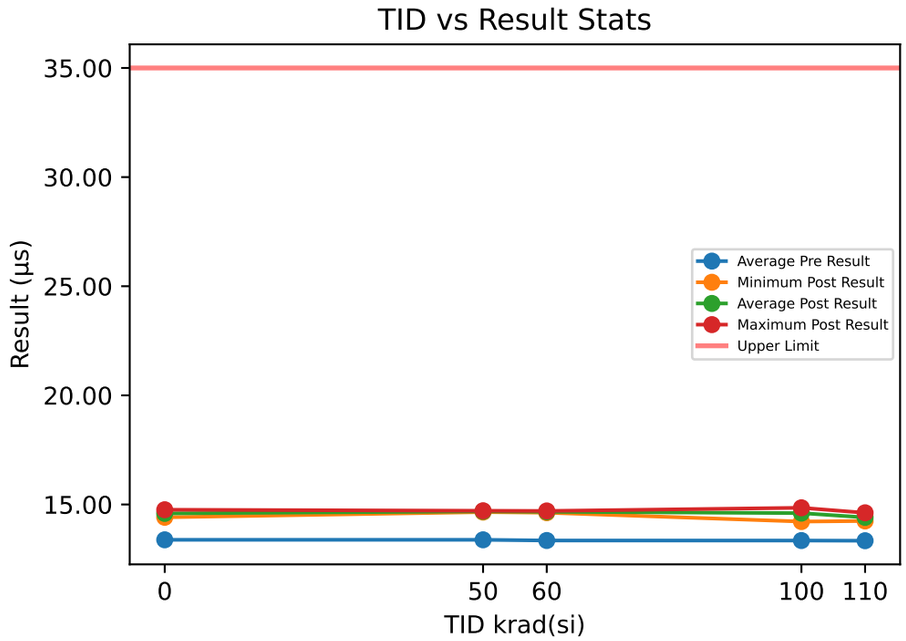
Test Results (Upper Limit = 35.0 (µs))

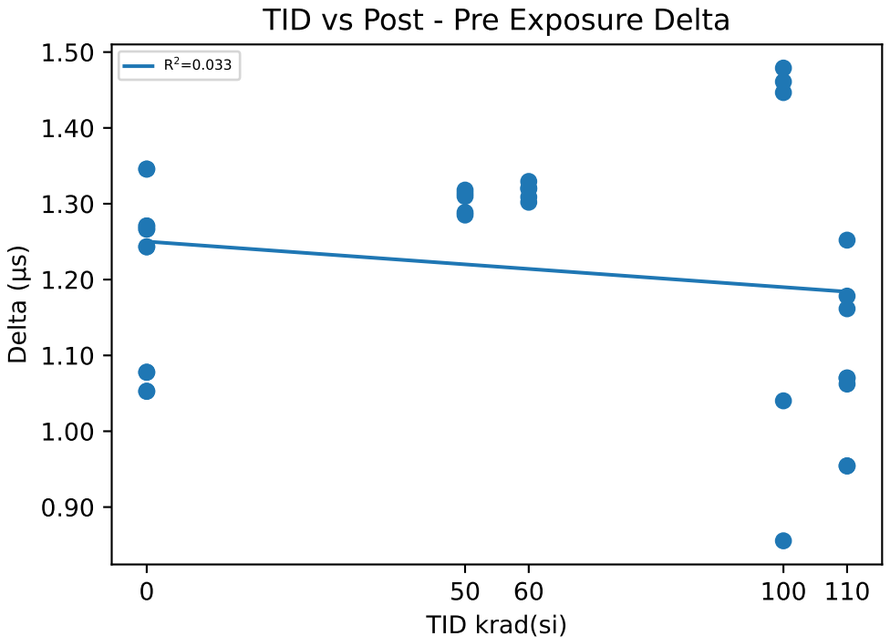
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	14.301	15.54	1.2389
2	0	CU2	14.317	15.465	1.1479
3	0	CU3	14.254	15.479	1.225
11	50	Unbiased-50k	14.295	15.523	1.2284
12	50	Unbiased-50k	14.32	15.522	1.202
13	50	Unbiased-50k	14.318	15.491	1.173
14	50	Unbiased-50k	14.228	15.466	1.2377
16	50	Unbiased-50k	14.364	15.443	1.0783
17	60	Biased-50k	14.336	15.61	1.2738
18	60	Biased-50k	14.287	15.642	1.3549
19	60	Biased-50k	14.293	15.6	1.307
20	60	Biased-50k	14.267	15.478	1.2118
21	60	Biased-50k	14.302	15.476	1.1738
24	100	Unbiased-100k	14.358	13.689	-0.6685
25	100	Unbiased-100k	14.308	13.667	-0.6418
26	100	Unbiased-100k	14.306	13.677	-0.6287
27	100	Unbiased-100k	14.282	13.642	-0.6398
28	100	Unbiased-100k	14.261	13.606	-0.6552
29	110	Biased-100k	14.286	13.678	-0.6078
30	110	Biased-100k	14.366	13.726	-0.6397
31	110	Biased-100k	14.251	13.667	-0.5838
32	110	Biased-100k	14.44	13.673	-0.7664
34	110	Biased-100k	14.293	13.675	-0.6183

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.254	14.291	14.317	0.032995	15.465	15.495	15.54	0.039844	1.1479	1.2039	1.2389	0.049021
50	14.228	14.305	14.364	0.049935	15.443	15.489	15.523	0.035078	1.0783	1.1839	1.2377	0.064173
60	14.267	14.297	14.336	0.025389	15.476	15.561	15.642	0.078293	1.1738	1.2643	1.3549	0.072575
100	14.261	14.303	14.358	0.036026	13.606	13.656	13.689	0.032924	-0.6685	-0.6468	-0.6287	0.015355
110	14.251	14.327	14.44	0.075453	13.667	13.684	13.726	0.023815	-0.7664	-0.6432	-0.5838	0.07175

evice Test: 36.12 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN4/7/7///90.9/634//0///@T_DISABLE_DELA





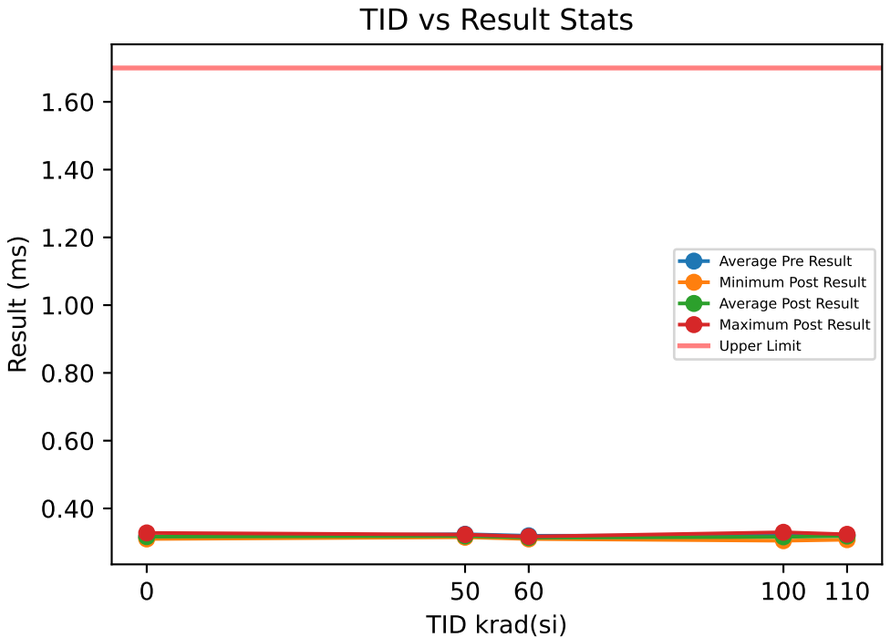
Test Results (Upper Limit = 35.0 (µs))

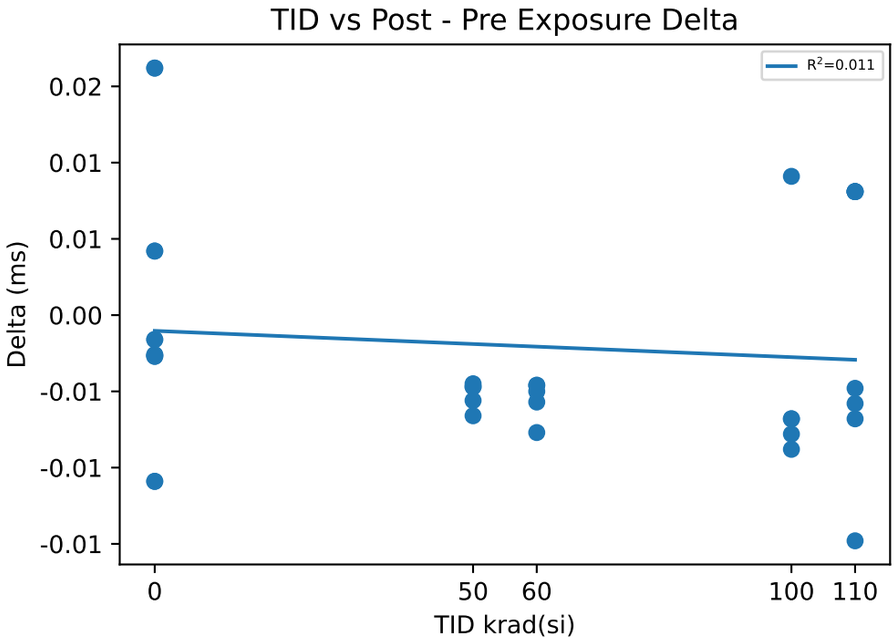
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	13.36	14.631	1.2707
2	0	CU2	13.37	14.636	1.2665
3	0	CU3	13.413	14.656	1.2432
11	50	Unbiased-50k	13.392	14.71	1.318
12	50	Unbiased-50k	13.371	14.685	1.3137
13	50	Unbiased-50k	13.379	14.664	1.2851
14	50	Unbiased-50k	13.363	14.651	1.2886
16	50	Unbiased-50k	13.402	14.712	1.3097
17	60	Biased-50k	13.384	14.704	1.3195
18	60	Biased-50k	13.328	14.657	1.3294
19	60	Biased-50k	13.37	14.69	1.3208
20	60	Biased-50k	13.315	14.623	1.3089
21	60	Biased-50k	13.351	14.653	1.302
24	100	Unbiased-100k	13.369	14.848	1.4789
25	100	Unbiased-100k	13.37	14.816	1.4466
26	100	Unbiased-100k	13.362	14.218	0.8555
27	100	Unbiased-100k	13.317	14.778	1.4609
28	100	Unbiased-100k	13.319	14.359	1.0401
29	110	Biased-100k	13.386	14.448	1.0622
30	110	Biased-100k	13.322	14.5	1.1782
31	110	Biased-100k	13.333	14.495	1.1615
32	110	Biased-100k	13.366	14.618	1.252
34	110	Biased-100k	13.289	14.359	1.0702

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.36	13.381	13.413	0.02837	14.631	14.641	14.656	0.013571	1.2432	1.2601	1.2707	0.014814
50	13.363	13.381	13.402	0.0161	14.651	14.685	14.712	0.02723	1.2851	1.303	1.318	0.015101
60	13.315	13.349	13.384	0.028636	14.623	14.666	14.704	0.03182	1.302	1.3161	1.3294	0.010738
100	13.317	13.347	13.37	0.027003	14.218	14.604	14.848	0.29328	0.8555	1.2564	1.4789	0.2894
110	13.289	13.339	13.386	0.038038	14.359	14.484	14.618	0.093844	1.0622	1.1448	1.252	0.079489

ce Test: 36.2 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN2/7/7///90.9/634//0///@T_ENABLE_DELAY_





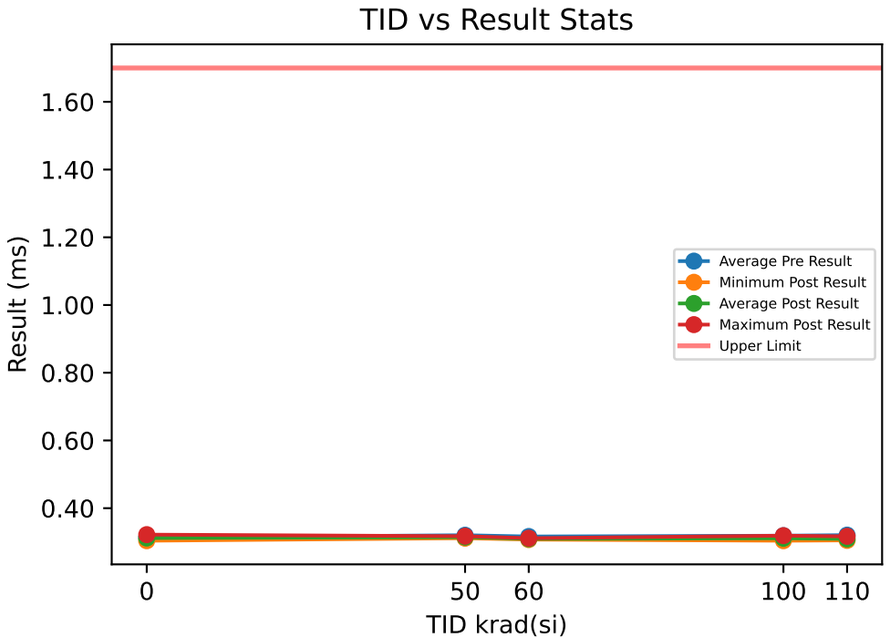
Test Results (Upper Limit = 1.7 (ms))

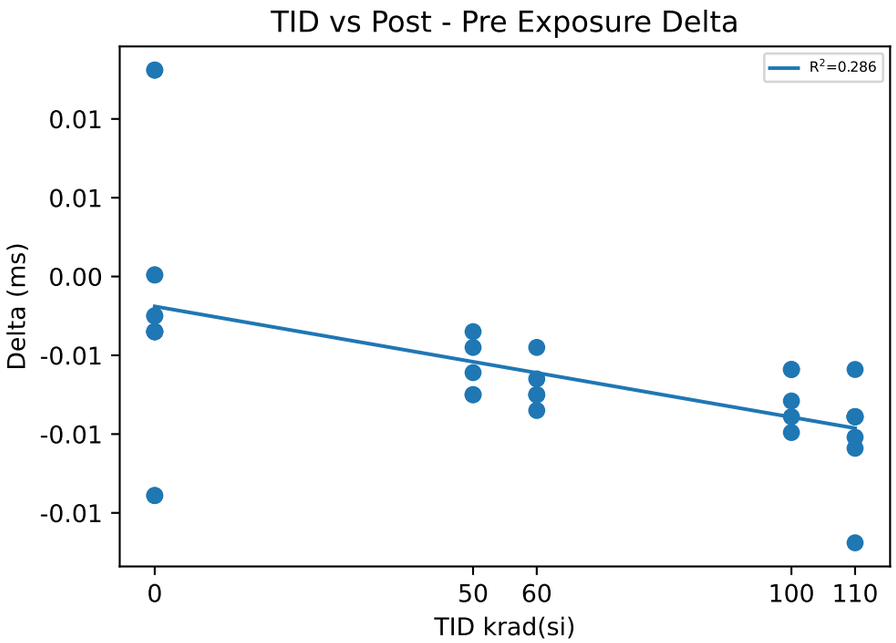
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3115	0.3099	-0.0016
2	0	CU2	0.3225	0.3198	-0.0027
3	0	CU3	0.3145	0.3119	-0.0026
11	50	Unbiased-50k	0.3275	0.3228	-0.0047
12	50	Unbiased-50k	0.3235	0.3169	-0.0066
13	50	Unbiased-50k	0.3205	0.3149	-0.0056
14	50	Unbiased-50k	0.3224	0.3179	-0.0045
16	50	Unbiased-50k	0.3255	0.3208	-0.0047
17	60	Biased-50k	0.3215	0.3169	-0.0046
18	60	Biased-50k	0.3215	0.3138	-0.0077
19	60	Biased-50k	0.3165	0.3119	-0.0046
20	60	Biased-50k	0.3215	0.3165	-0.005
21	60	Biased-50k	0.3156	0.3099	-0.0057
24	100	Unbiased-100k	0.3275	0.3207	-0.0068
25	100	Unbiased-100k	0.3205	0.3296	0.0091
26	100	Unbiased-100k	0.3185	0.3117	-0.0068
27	100	Unbiased-100k	0.3225	0.3137	-0.0088
28	100	Unbiased-100k	0.3125	0.3047	-0.0078
29	110	Biased-100k	0.3175	0.3107	-0.0068
30	110	Biased-100k	0.3205	0.3157	-0.0048
31	110	Biased-100k	0.3245	0.3187	-0.0058
32	110	Biased-100k	0.3225	0.3077	-0.0148
34	110	Biased-100k	0.3155	0.3236	0.0081

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3115	0.31617	0.3225	0.0056862	0.3099	0.31387	0.3198	0.0052348	-0.0027	-0.0023	-0.0016	0.00060828
50	0.3205	0.32388	0.3275	0.0027151	0.3149	0.31866	0.3228	0.0031437	-0.0066	-0.00522	-0.0045	0.00088148
60	0.3156	0.31932	0.3215	0.003002	0.3099	0.3138	0.3169	0.0029883	-0.0077	-0.00552	-0.0046	0.0012988
100	0.3125	0.3203	0.3275	0.0054955	0.3047	0.31608	0.3296	0.0094669	-0.0088	-0.00422	0.0091	0.0074921
110	0.3155	0.3201	0.3245	0.0036469	0.3077	0.31528	0.3236	0.0063152	-0.0148	-0.00482	0.0081	0.0082372

ce Test: 36.3 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN3/7/7///90.9/634//0///@T_ENABLE_DELAY_





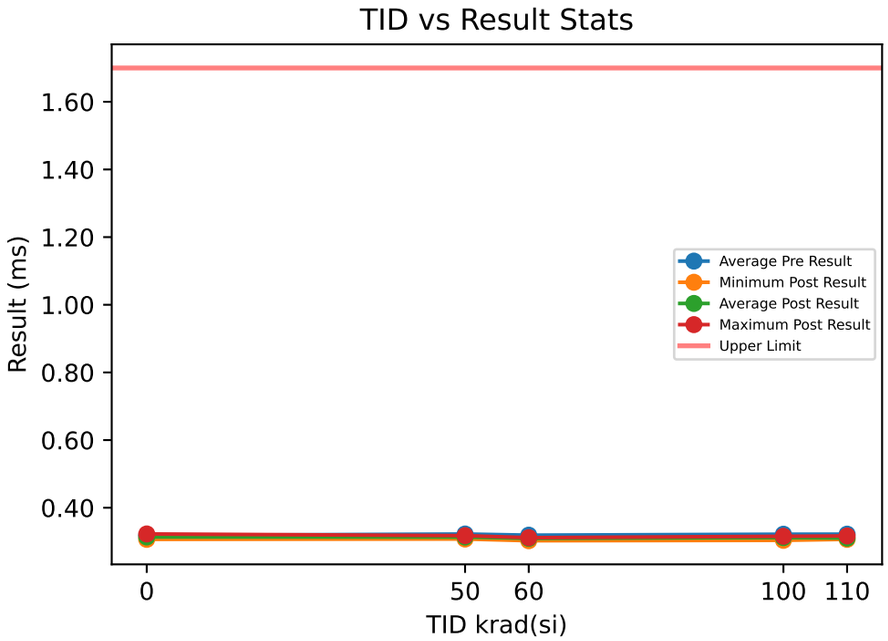
Test Results (Upper Limit = 1.7 (ms))

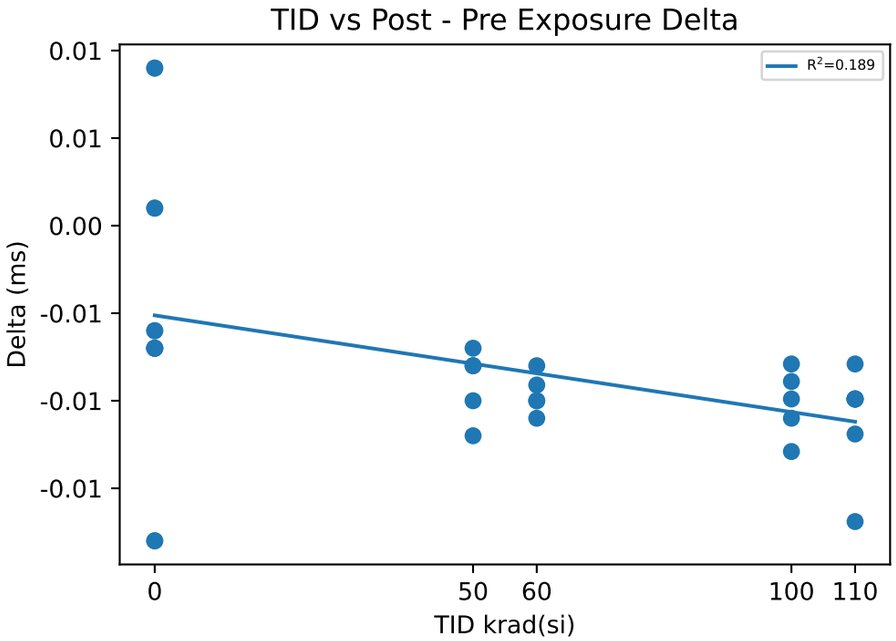
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3088	0.3053	-0.0035
2	0	CU2	0.3178	0.3153	-0.0025
3	0	CU3	0.3138	0.3103	-0.0035
11	50	Unbiased-50k	0.3248	0.3173	-0.0075
12	50	Unbiased-50k	0.3188	0.3113	-0.0075
13	50	Unbiased-50k	0.3178	0.3117	-0.0061
14	50	Unbiased-50k	0.3188	0.3143	-0.0045
16	50	Unbiased-50k	0.3208	0.3173	-0.0035
17	60	Biased-50k	0.3168	0.3093	-0.0075
18	60	Biased-50k	0.3188	0.3103	-0.0085
19	60	Biased-50k	0.3158	0.3093	-0.0065
20	60	Biased-50k	0.3188	0.3113	-0.0075
21	60	Biased-50k	0.3118	0.3073	-0.0045
24	100	Unbiased-100k	0.3268	0.3189	-0.0079
25	100	Unbiased-100k	0.3178	0.3119	-0.0059
26	100	Unbiased-100k	0.3198	0.3109	-0.0089
27	100	Unbiased-100k	0.3198	0.3099	-0.0099
28	100	Unbiased-100k	0.3098	0.3039	-0.0059
29	110	Biased-100k	0.3171	0.3069	-0.0102
30	110	Biased-100k	0.3188	0.3129	-0.0059
31	110	Biased-100k	0.3278	0.3169	-0.0109
32	110	Biased-100k	0.3218	0.3049	-0.0169
34	110	Biased-100k	0.3168	0.3079	-0.0089

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3088	0.31347	0.3178	0.0045092	0.3053	0.3103	0.3153	0.005	-0.0035	-0.0031667	-0.0025	0.00057735
50	0.3178	0.3202	0.3248	0.0027928	0.3113	0.31438	0.3173	0.0029038	-0.0075	-0.00582	-0.0035	0.0017922
60	0.3118	0.3164	0.3188	0.002881	0.3073	0.3095	0.3113	0.0014832	-0.0085	-0.0069	-0.0045	0.0015166
100	0.3098	0.3188	0.3268	0.0060828	0.3039	0.3111	0.3189	0.0053572	-0.0099	-0.0077	-0.0059	0.0017889
110	0.3168	0.32046	0.3278	0.0045583	0.3049	0.3099	0.3169	0.004899	-0.0169	-0.01056	-0.0059	0.0040284

ce Test: 36.4 T_ENABLE_DELAY_VIN(EnableDelay|EnRisingToSwRising/EN4/7/7///90.9/634//0///@T_ENABLE_DELAY_





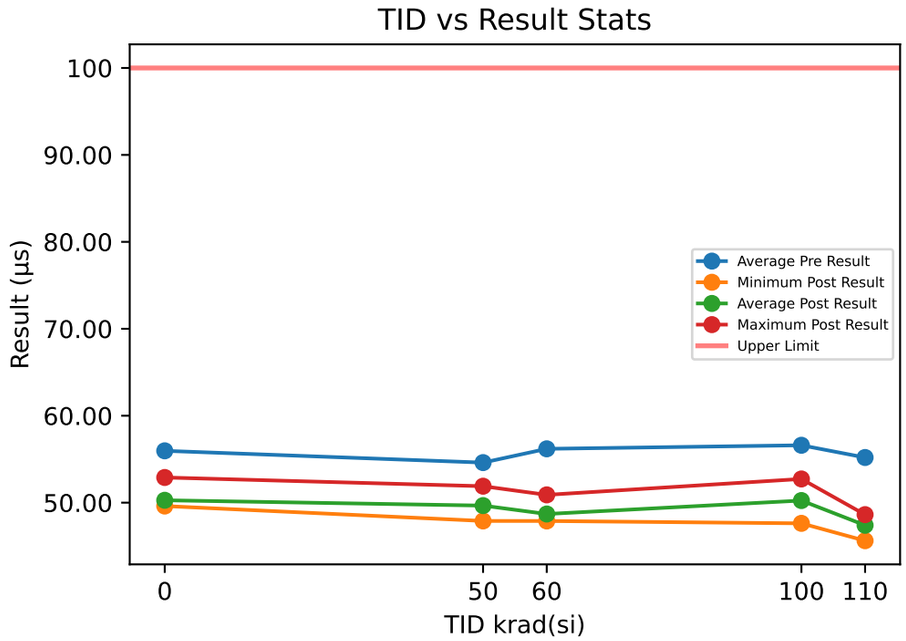
Test Results (Upper Limit = 1.7 (ms))

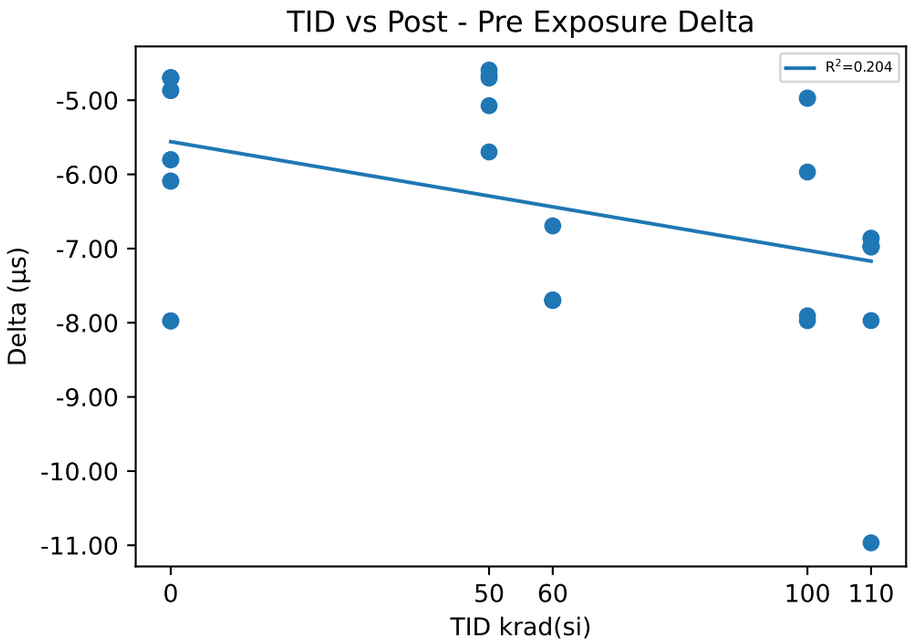
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.3135	0.3075	-0.006
2	0	CU2	0.3245	0.3175	-0.007
3	0	CU3	0.3165	0.3095	-0.007
11	50	Unbiased-50k	0.3255	0.3175	-0.008
12	50	Unbiased-50k	0.3195	0.3075	-0.012
13	50	Unbiased-50k	0.3225	0.3125	-0.01
14	50	Unbiased-50k	0.3205	0.3125	-0.008
16	50	Unbiased-50k	0.3235	0.3165	-0.007
17	60	Biased-50k	0.3215	0.3115	-0.01
18	60	Biased-50k	0.3195	0.3095	-0.01
19	60	Biased-50k	0.3206	0.3115	-0.0091
20	60	Biased-50k	0.3225	0.3115	-0.011
21	60	Biased-50k	0.3105	0.3025	-0.008
24	100	Unbiased-100k	0.3285	0.3156	-0.0129
25	100	Unbiased-100k	0.3225	0.3146	-0.0079
26	100	Unbiased-100k	0.3225	0.3126	-0.0099
27	100	Unbiased-100k	0.3226	0.3116	-0.011
28	100	Unbiased-100k	0.3125	0.3036	-0.0089
29	110	Biased-100k	0.3185	0.3066	-0.0119
30	110	Biased-100k	0.3215	0.3136	-0.0079
31	110	Biased-100k	0.3265	0.3166	-0.0099
32	110	Biased-100k	0.3235	0.3066	-0.0169
34	110	Biased-100k	0.3195	0.3096	-0.0099

Test Statistics (ms)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3135	0.31817	0.3245	0.0056862	0.3075	0.3115	0.3175	0.0052915	-0.007	-0.0066667	-0.006	0.00057735
50	0.3195	0.3223	0.3255	0.0023875	0.3075	0.3133	0.3175	0.0039623	-0.012	-0.009	-0.007	0.002
60	0.3105	0.31892	0.3225	0.0048355	0.3025	0.3093	0.3115	0.0038987	-0.011	-0.00962	-0.008	0.0011278
100	0.3125	0.32172	0.3285	0.0057656	0.3036	0.3116	0.3156	0.0047434	-0.0129	-0.01012	-0.0079	0.0019344
110	0.3185	0.3219	0.3265	0.0032094	0.3066	0.3106	0.3166	0.0044159	-0.0169	-0.0113	-0.0079	0.0034351

Device Test: 36.5 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN1/7/7///90.9/634//0///@T_ENABLE_DELAY)





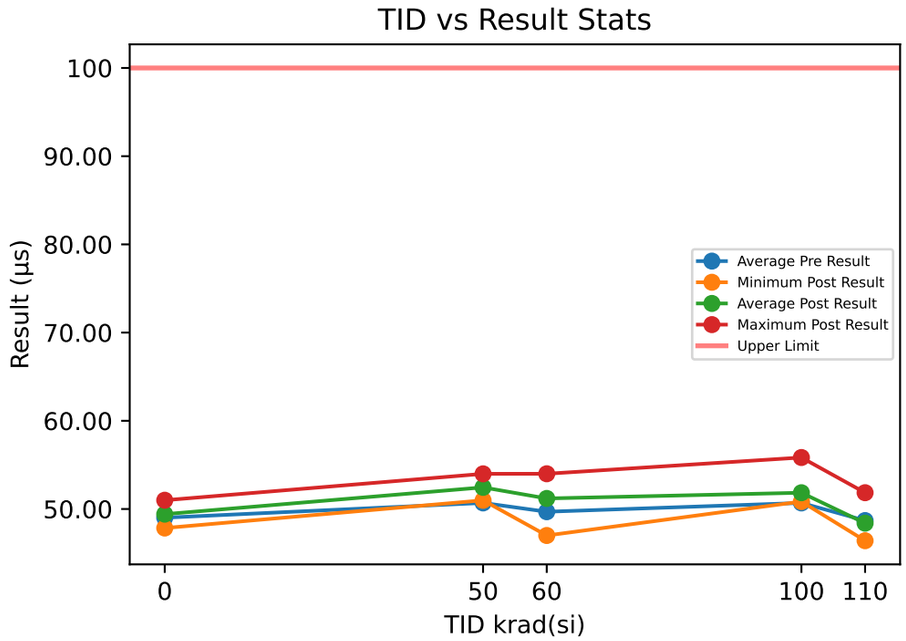
Test Results (Upper Limit = 100.0 (µs))

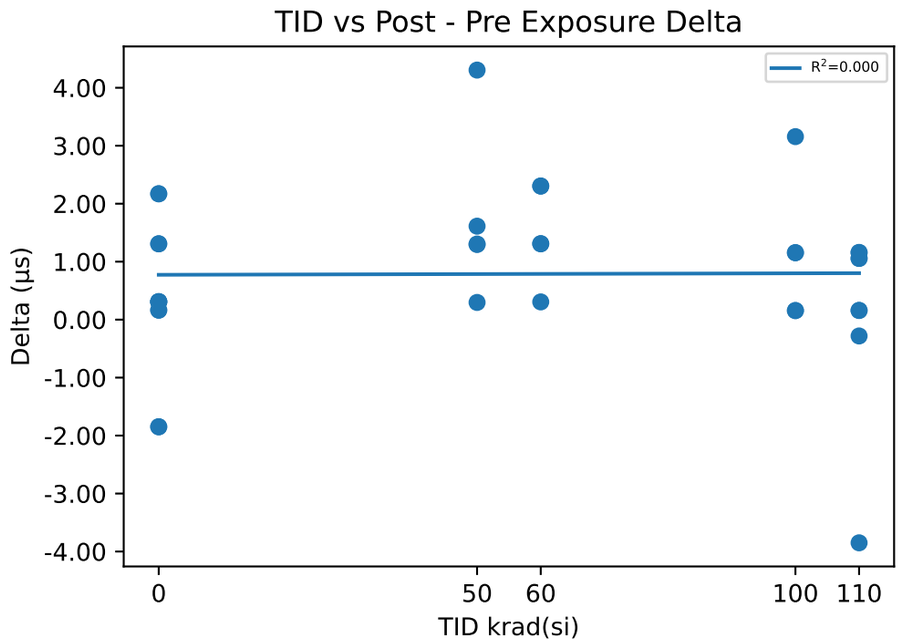
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	55.702	49.899	-5.8024
2	0	CU2	54.594	49.895	-4.6989
3	0	CU3	57.592	52.895	-4.6977
11	50	Unbiased-50k	56.594	51.892	-4.7014
12	50	Unbiased-50k	53.593	48.999	-4.5937
13	50	Unbiased-50k	54.665	50.002	-4.6623
14	50	Unbiased-50k	53.593	47.896	-5.6976
16	50	Unbiased-50k	54.593	49.519	-5.0741
17	60	Biased-50k	55.593	47.896	-7.6965
18	60	Biased-50k	55.592	47.892	-7.6999
19	60	Biased-50k	56.593	48.896	-7.6967
20	60	Biased-50k	55.592	47.897	-7.6943
21	60	Biased-50k	57.592	50.897	-6.6946
24	100	Unbiased-100k	55.593	47.621	-7.972
25	100	Unbiased-100k	56.528	48.621	-7.9071
26	100	Unbiased-100k	57.593	52.622	-4.9713
27	100	Unbiased-100k	57.699	52.726	-4.9733
28	100	Unbiased-100k	55.591	49.623	-5.9682
29	110	Biased-100k	56.594	48.623	-7.9712
30	110	Biased-100k	55.592	48.622	-6.9696
31	110	Biased-100k	52.602	45.622	-6.9798
32	110	Biased-100k	56.592	45.625	-10.967
34	110	Biased-100k	54.59	47.728	-6.8627

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54.594	55.963	57.592	1.5163	49.895	50.896	52.895	1.7307	-5.8024	-5.0663	-4.6977	0.63745
50	53.593	54.608	56.594	1.2254	47.896	49.662	51.892	1.4722	-5.6976	-4.9458	-4.5937	0.45982
60	55.592	56.192	57.592	0.89437	47.892	48.696	50.897	1.3047	-7.6999	-7.4964	-6.6946	0.44822
100	55.591	56.601	57.699	1.0286	47.621	50.243	52.726	2.33	-7.972	-6.3584	-4.9713	1.4997
110	52.602	55.194	56.594	1.67	45.622	47.244	48.623	1.5238	-10.967	-7.9501	-6.8627	1.7456

Device Test: 36.6 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN2/7/7///90.9/634//0///@T_ENABLE_DELAY)





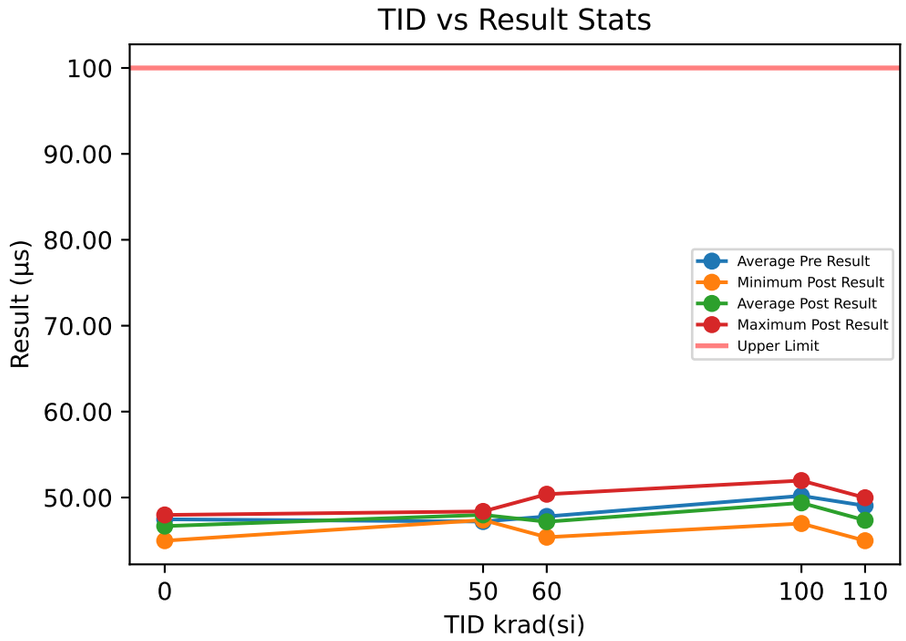
Test Results (Upper Limit = 100.0 (µs))

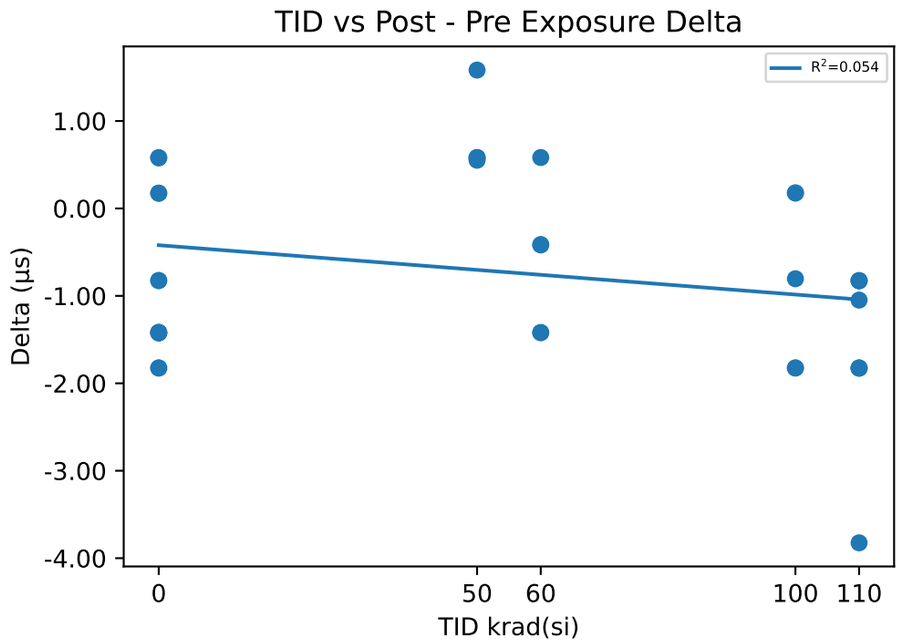
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	47.667	47.978	0.3104
2	0	CU2	49.689	49.996	0.307
3	0	CU3	49.686	50.994	1.308
11	50	Unbiased-50k	50.69	52.302	1.6123
12	50	Unbiased-50k	53.691	53.987	0.2965
13	50	Unbiased-50k	49.688	50.984	1.2964
14	50	Unbiased-50k	50.689	51.993	1.3042
16	50	Unbiased-50k	48.687	52.992	4.305
17	60	Biased-50k	49.69	51.996	2.3056
18	60	Biased-50k	49.692	51.995	2.3035
19	60	Biased-50k	46.691	46.996	0.3059
20	60	Biased-50k	49.688	50.999	1.3108
21	60	Biased-50k	52.687	53.995	1.3078
24	100	Unbiased-100k	49.691	50.845	1.1532
25	100	Unbiased-100k	50.691	50.846	0.1554
26	100	Unbiased-100k	50.689	50.847	0.1573
27	100	Unbiased-100k	52.68	55.837	3.1571
28	100	Unbiased-100k	49.688	50.844	1.1565
29	110	Biased-100k	50.691	51.847	1.1565
30	110	Biased-100k	46.685	46.404	-0.2818
31	110	Biased-100k	47.69	48.849	1.1596
32	110	Biased-100k	50.692	46.842	-3.8499
34	110	Biased-100k	47.69	48.747	1.0564

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.667	49.014	49.689	1.1664	47.978	49.656	50.994	1.5367	0.307	0.6418	1.308	0.57695
50	48.687	50.689	53.691	1.8722	50.984	52.452	53.987	1.1219	0.2965	1.7629	4.305	1.5053
60	46.691	49.689	52.687	2.12	46.996	51.196	53.995	2.5878	0.3059	1.5067	2.3056	0.83561
100	49.688	50.688	52.68	1.2207	50.844	51.844	55.837	2.2323	0.1554	1.1559	3.1571	1.2251
110	46.685	48.69	50.692	1.8726	46.404	48.538	51.847	2.1519	-3.8499	-0.15184	1.1596	2.1555

Device Test: 36.7 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN3/7/7///90.9/634//0///@T_ENABLE_DELAY)





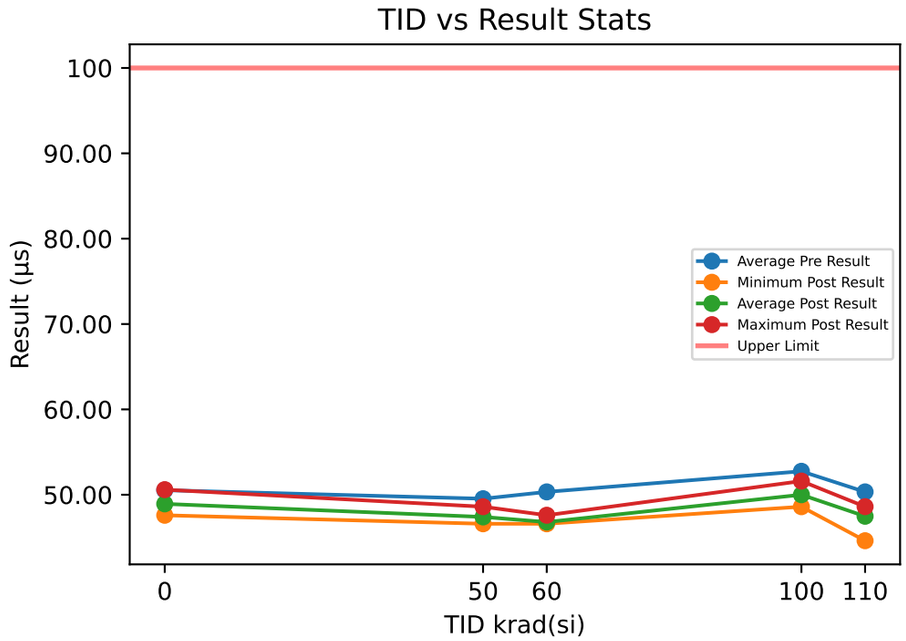
Test Results (Upper Limit = 100.0 (µs))

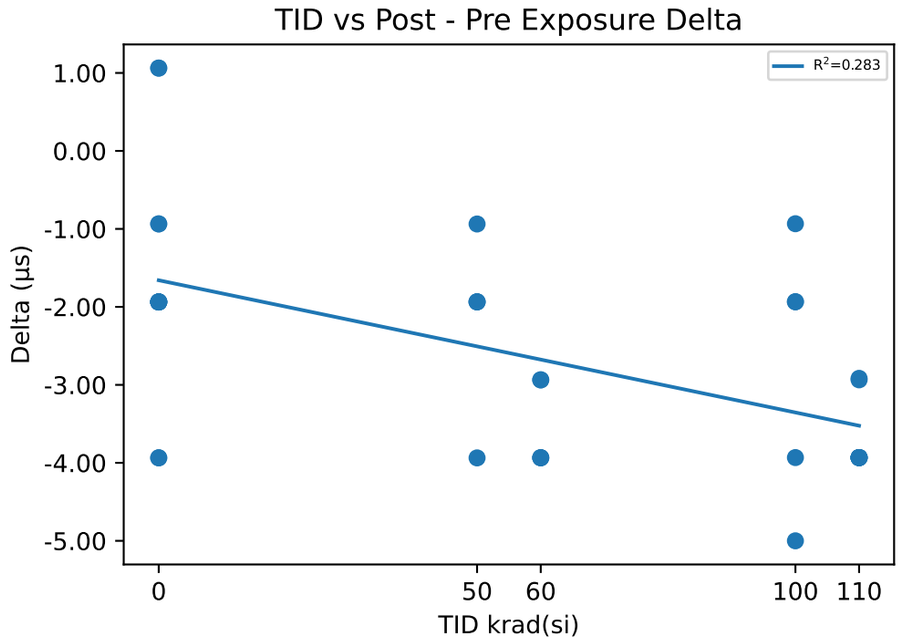
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	46.798	45.375	-1.4233
2	0	CU2	46.796	47.376	0.5799
3	0	CU3	48.796	47.378	-1.4179
11	50	Unbiased-50k	47.796	48.379	0.5829
12	50	Unbiased-50k	47.828	48.38	0.5513
13	50	Unbiased-50k	46.798	48.381	1.5824
14	50	Unbiased-50k	46.797	47.377	0.5802
16	50	Unbiased-50k	46.797	47.376	0.5798
17	60	Biased-50k	46.797	46.38	-0.4175
18	60	Biased-50k	48.799	47.379	-1.4207
19	60	Biased-50k	45.798	46.381	0.5824
20	60	Biased-50k	46.799	45.38	-1.4194
21	60	Biased-50k	50.796	50.383	-0.4135
24	100	Unbiased-100k	50.794	49.989	-0.8043
25	100	Unbiased-100k	47.796	47.973	0.1765
26	100	Unbiased-100k	51.798	49.974	-1.8246
27	100	Unbiased-100k	51.796	51.973	0.1774
28	100	Unbiased-100k	48.798	46.973	-1.8247
29	110	Biased-100k	49.799	47.975	-1.8246
30	110	Biased-100k	46.022	44.973	-1.0483
31	110	Biased-100k	50.8	49.974	-0.826
32	110	Biased-100k	49.798	45.974	-3.8243
34	110	Biased-100k	48.799	47.973	-0.8265

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.796	47.464	48.796	1.1539	45.375	46.71	47.378	1.1559	-1.4233	-0.75377	0.5799	1.155
50	46.797	47.203	47.828	0.55619	47.376	47.979	48.381	0.54948	0.5513	0.77532	1.5824	0.45136
60	45.798	47.798	50.796	1.9993	45.38	47.18	50.383	1.9245	-1.4207	-0.61774	0.5824	0.83809
100	47.796	50.197	51.798	1.8164	46.973	49.377	51.973	1.9507	-1.8247	-0.81994	0.1774	1.0008
110	46.022	49.044	50.8	1.8314	44.973	47.374	49.974	1.9494	-3.8243	-1.6699	-0.826	1.2723

Device Test: 36.8 T_ENABLE_DELAY(EnableDelay|EnRisingToSwRising/EN4/7/7///90.9/634//0///@T_ENABLE_DELAY)





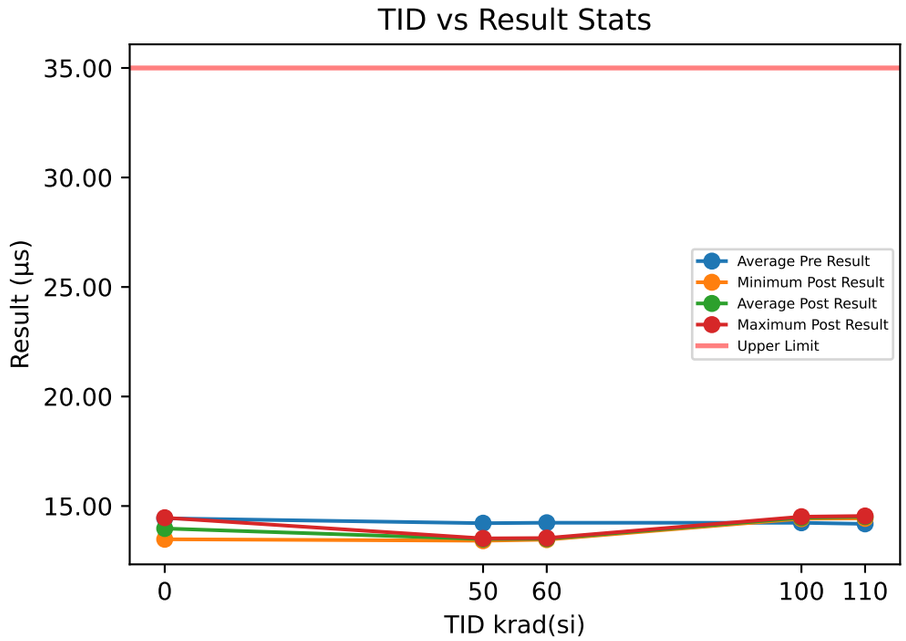
Test Results (Upper Limit = 100.0 (µs))

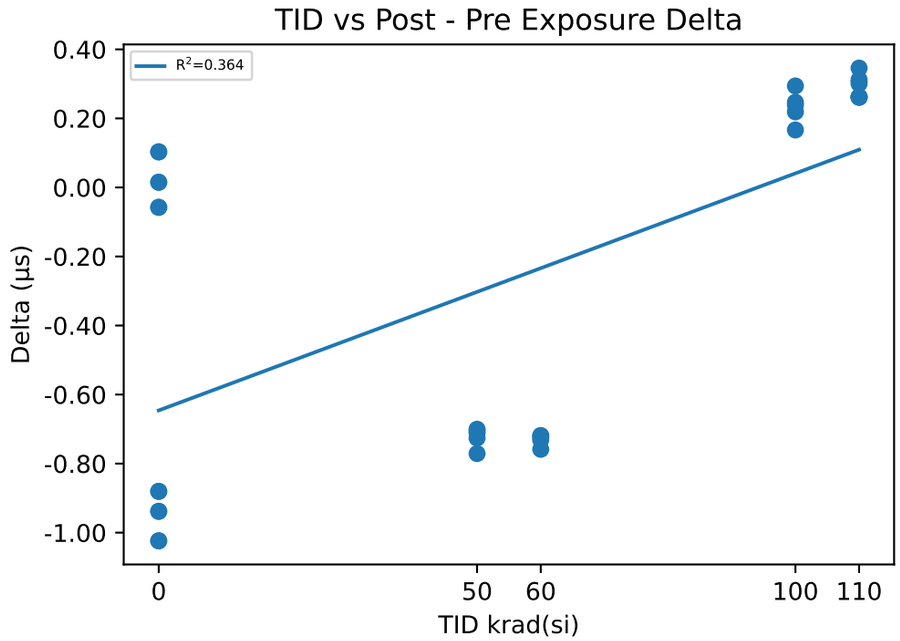
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	49.532	47.596	-1.9368
2	0	CU2	52.533	50.596	-1.9379
3	0	CU3	49.534	48.599	-0.9358
11	50	Unbiased-50k	48.533	47.596	-0.937
12	50	Unbiased-50k	48.536	46.599	-1.937
13	50	Unbiased-50k	52.535	48.598	-3.9366
14	50	Unbiased-50k	48.534	46.599	-1.935
16	50	Unbiased-50k	49.534	47.599	-1.9343
17	60	Biased-50k	50.534	46.601	-3.9334
18	60	Biased-50k	49.534	46.6	-2.9347
19	60	Biased-50k	51.533	47.599	-3.935
20	60	Biased-50k	49.536	46.599	-2.9369
21	60	Biased-50k	50.533	46.598	-3.9349
24	100	Unbiased-100k	50.533	48.598	-1.9354
25	100	Unbiased-100k	53.534	51.601	-1.9332
26	100	Unbiased-100k	54.535	50.602	-3.9325
27	100	Unbiased-100k	55.603	50.603	-5
28	100	Unbiased-100k	49.536	48.602	-0.9336
29	110	Biased-100k	50.536	47.601	-2.9355
30	110	Biased-100k	47.53	44.613	-2.9165
31	110	Biased-100k	50.534	46.601	-3.9333
32	110	Biased-100k	50.535	46.601	-3.9334
34	110	Biased-100k	52.536	48.604	-3.9325

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.532	50.533	52.533	1.7321	47.596	48.93	50.596	1.5272	-1.9379	-1.6035	-0.9358	0.57825
50	48.533	49.535	52.535	1.7322	46.599	47.399	48.598	0.83608	-3.9366	-2.136	-0.937	1.0955
60	49.534	50.334	51.533	0.83584	46.598	46.799	47.599	0.44679	-3.935	-3.535	-2.9347	0.54697
100	49.536	52.748	55.603	2.6071	48.598	50.001	51.601	1.3426	-5	-2.7469	-0.9336	1.6651
110	47.53	50.334	52.536	1.7913	44.613	46.804	48.604	1.4796	-3.9334	-3.5302	-2.9165	0.55163

Device Test: 36.9 T_DISABLE_DELAY(EnableDelay|EnFallingToSwFalling/EN1/7/7///90.9/634//0///@T_DISABLE_DELAY





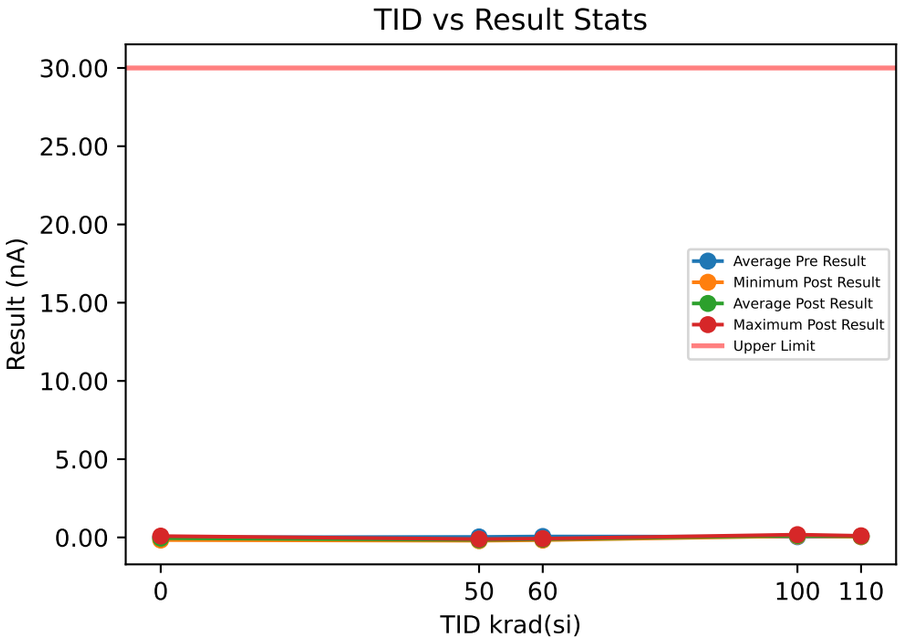
Test Results (Upper Limit = 35.0 (µs))

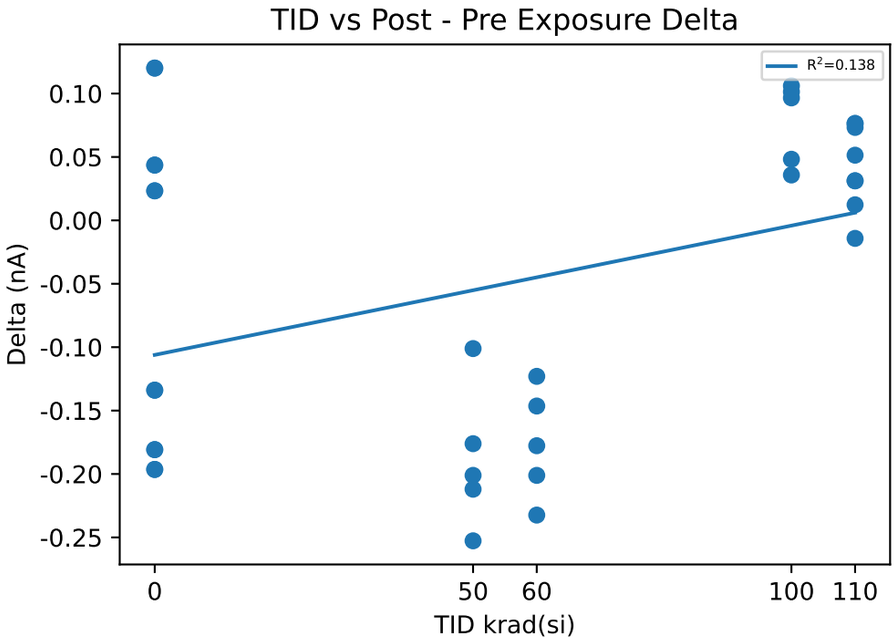
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	14.506	13.482	-1.0237
2	0	CU2	14.444	13.506	-0.9382
3	0	CU3	14.363	13.482	-0.8804
11	50	Unbiased-50k	14.248	13.522	-0.7259
12	50	Unbiased-50k	14.116	13.416	-0.7004
13	50	Unbiased-50k	14.216	13.505	-0.7114
14	50	Unbiased-50k	14.292	13.521	-0.7709
16	50	Unbiased-50k	14.207	13.501	-0.7057
17	60	Biased-50k	14.203	13.484	-0.7187
18	60	Biased-50k	14.184	13.465	-0.7195
19	60	Biased-50k	14.269	13.537	-0.7314
20	60	Biased-50k	14.242	13.516	-0.7253
21	60	Biased-50k	14.286	13.527	-0.7585
24	100	Unbiased-100k	14.196	14.49	0.294
25	100	Unbiased-100k	14.223	14.441	0.2189
26	100	Unbiased-100k	14.255	14.421	0.1665
27	100	Unbiased-100k	14.274	14.513	0.2384
28	100	Unbiased-100k	14.226	14.473	0.2469
29	110	Biased-100k	14.226	14.526	0.3004
30	110	Biased-100k	14.129	14.435	0.3066
31	110	Biased-100k	14.146	14.459	0.3123
32	110	Biased-100k	14.143	14.489	0.3458
34	110	Biased-100k	14.284	14.546	0.2622

Test Statistics (µs)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	14.363	14.438	14.506	0.071742	13.482	13.49	13.506	0.013886	-1.0237	-0.94743	-0.8804	0.072095
50	14.116	14.216	14.292	0.064932	13.416	13.493	13.522	0.044212	-0.7709	-0.72286	-0.7004	0.028493
60	14.184	14.237	14.286	0.042901	13.465	13.506	13.537	0.030509	-0.7585	-0.73068	-0.7187	0.01637
100	14.196	14.235	14.274	0.030414	14.421	14.468	14.513	0.036619	0.1665	0.23294	0.294	0.046272
110	14.129	14.185	14.284	0.066698	14.435	14.491	14.546	0.045831	0.2622	0.30546	0.3458	0.029885

Device Test: 38.1 IVSNS_LKG(EA|Leakage/VSNS1/3/3///90.9/634//0///@IVSNS_LKG)





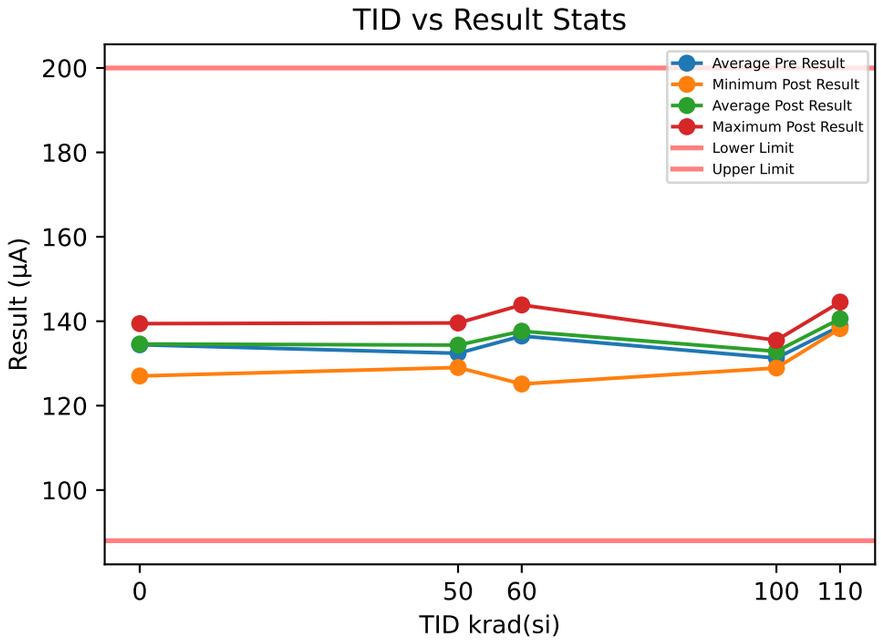
Test Results (Upper Limit = 30.0 (nA))

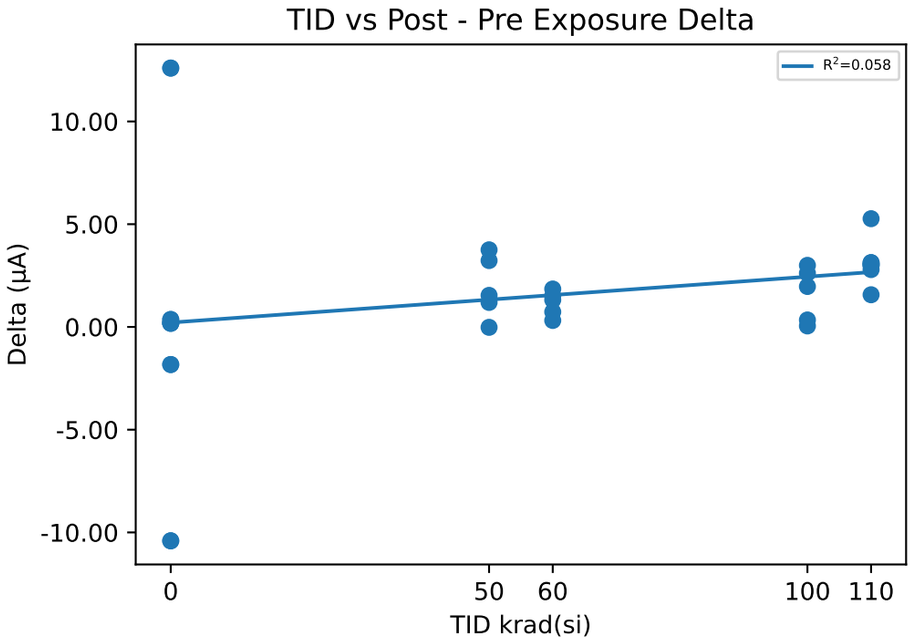
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.0224	-0.1584	-0.1808
2	0	CU2	-0.0354	-0.1693	-0.1339
3	0	CU3	0.0271	-0.1693	-0.1964
11	50	Unbiased-50k	0.0287	-0.1474	-0.1761
12	50	Unbiased-50k	0.0208	-0.1912	-0.212
13	50	Unbiased-50k	0.0709	-0.1302	-0.2011
14	50	Unbiased-50k	-0.0057	-0.1068	-0.1011
16	50	Unbiased-50k	0.0412	-0.2115	-0.2527
17	60	Biased-50k	0.1537	-0.0787	-0.2324
18	60	Biased-50k	0.0271	-0.174	-0.2011
19	60	Biased-50k	0.0412	-0.1365	-0.1777
20	60	Biased-50k	0.0599	-0.0865	-0.1464
21	60	Biased-50k	0.0146	-0.1084	-0.123
24	100	Unbiased-100k	0.0365	0.0847	0.0482
25	100	Unbiased-100k	0.0802	0.1768	0.0966
26	100	Unbiased-100k	0.0677	0.1035	0.0358
27	100	Unbiased-100k	0.0099	0.116	0.1061
28	100	Unbiased-100k	0.0224	0.1238	0.1014
29	110	Biased-100k	-0.0042	0.0691	0.0733
30	110	Biased-100k	0.0646	0.0769	0.0123
31	110	Biased-100k	0.0521	0.1035	0.0514
32	110	Biased-100k	0.1099	0.0957	-0.0142
34	110	Biased-100k	0.013	0.0442	0.0312

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0354	0.0047	0.0271	0.034807	-0.1693	-0.16567	-0.1584	0.0062931	-0.1964	-0.17037	-0.1339	0.03253
50	-0.0057	0.03118	0.0709	0.028072	-0.2115	-0.15742	-0.1068	0.043213	-0.2527	-0.1886	-0.1011	0.056181
60	0.0146	0.0593	0.1537	0.055395	-0.174	-0.11682	-0.0787	0.039052	-0.2324	-0.17612	-0.123	0.043298
100	0.0099	0.04334	0.0802	0.029814	0.0847	0.12096	0.1768	0.034534	0.0358	0.07762	0.1061	0.032982
110	-0.0042	0.04708	0.1099	0.044915	0.0442	0.07788	0.1035	0.023379	-0.0142	0.0308	0.0733	0.033904

Device Test: 38.10 EA_SOURCE(EA|SourceCurrent/COMP2/3/3///90.9/634//0///@EA_SOURCE)





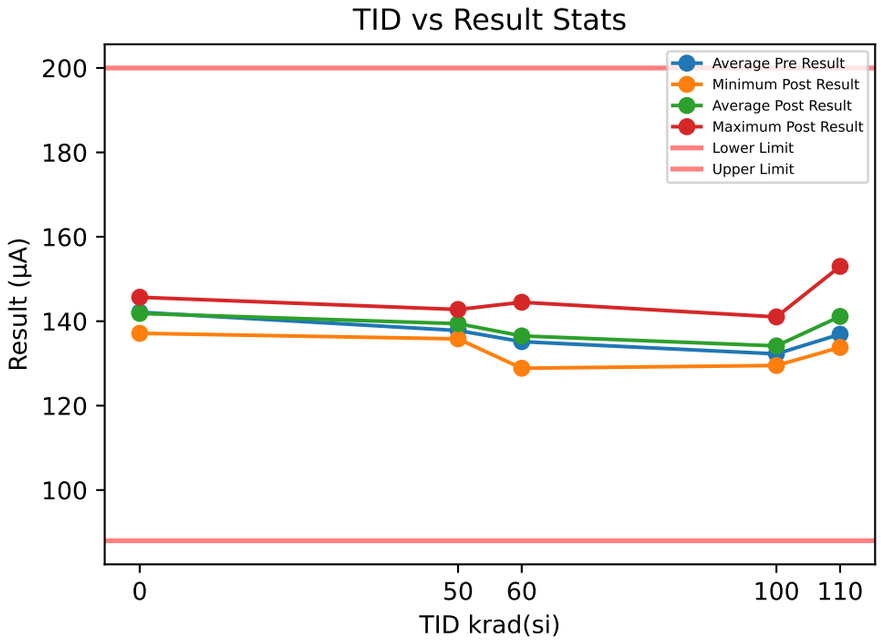
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

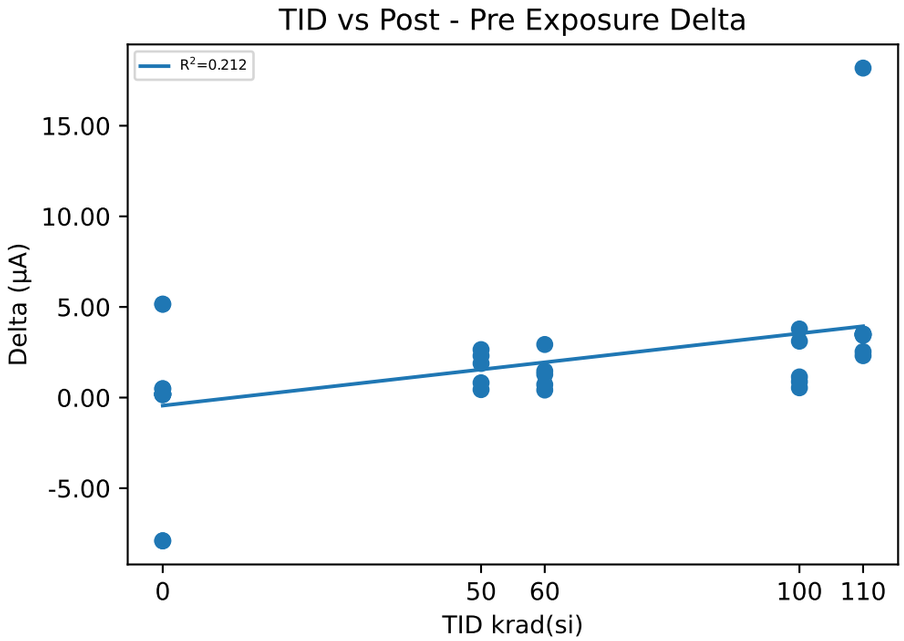
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	138.88	139.25	0.3614
2	0	CU2	126.84	127.03	0.1969
3	0	CU3	137.55	137.72	0.1768
11	50	Unbiased-50k	127.68	129.22	1.5365
12	50	Unbiased-50k	129.05	129.04	-0.0189
13	50	Unbiased-50k	136.36	139.59	3.2302
14	50	Unbiased-50k	133.4	137.15	3.7533
16	50	Unbiased-50k	135.53	136.73	1.1926
17	60	Biased-50k	141.76	143.6	1.8464
18	60	Biased-50k	124.4	125.13	0.7332
19	60	Biased-50k	137.55	139.07	1.52
20	60	Biased-50k	143.55	143.86	0.3149
21	60	Biased-50k	135.24	136.55	1.3151
24	100	Unbiased-100k	132.81	132.86	0.0483
25	100	Unbiased-100k	132.49	135.48	2.9973
26	100	Unbiased-100k	133.51	133.85	0.3402
27	100	Unbiased-100k	126.31	128.92	2.6161
28	100	Unbiased-100k	131.26	133.22	1.9687
29	110	Biased-100k	141.62	143.19	1.5662
30	110	Biased-100k	138.59	141.38	2.7917
31	110	Biased-100k	139.28	142.32	3.0371
32	110	Biased-100k	139.27	144.54	5.2679
34	110	Biased-100k	135.25	138.38	3.1287

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.84	134.42	138.88	6.6036	127.03	134.67	139.25	6.655	0.1768	0.24503	0.3614	0.10128
50	127.68	132.41	136.36	3.87	129.04	134.34	139.59	4.8857	-0.0189	1.9387	3.7533	1.542
60	124.4	136.5	143.55	7.5236	125.13	137.64	143.86	7.6475	0.3149	1.1459	1.8464	0.61647
100	126.31	131.27	133.51	2.8946	128.92	132.87	135.48	2.4241	0.0483	1.5941	2.9973	1.3337
110	135.25	138.8	141.62	2.2938	138.38	141.96	144.54	2.3146	1.5662	3.1583	5.2679	1.3356

Device Test: 38.11 EA_SOURCE(EA|SourceCurrent/COMP3/3/3///90.9/634//0///@EA_SOURCE)





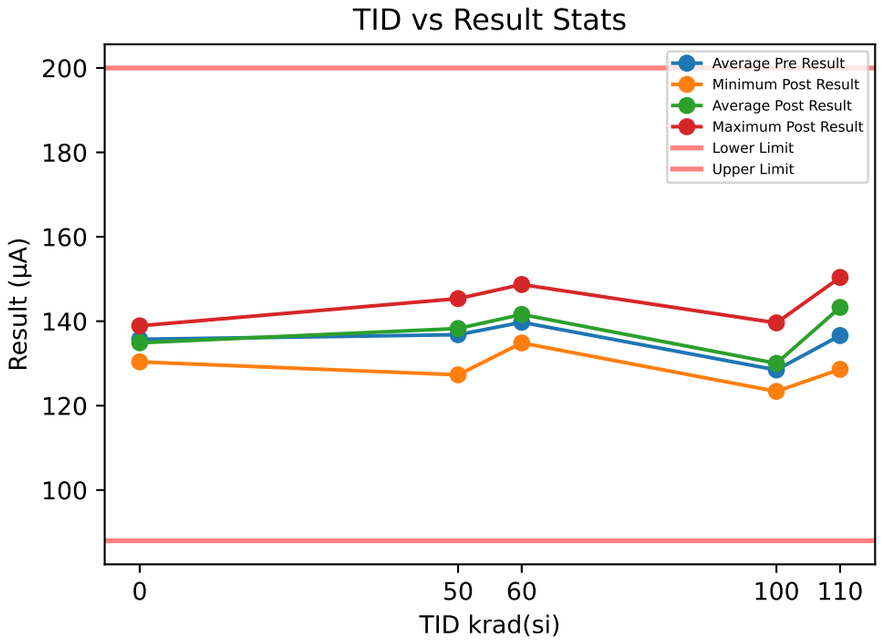
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

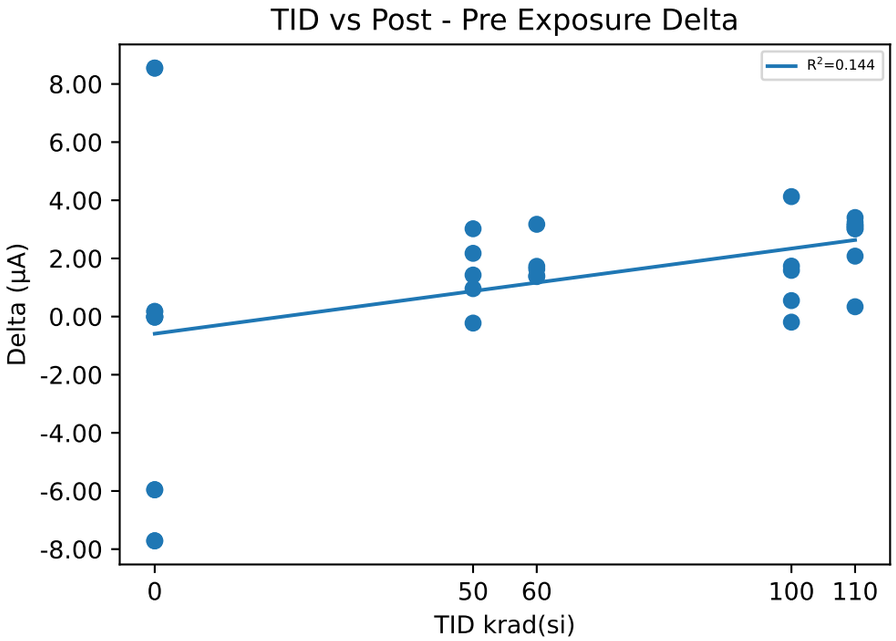
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	145.04	145.53	0.4877
2	0	CU2	140.53	140.72	0.189
3	0	CU3	140.84	141	0.1625
11	50	Unbiased-50k	136.15	138.8	2.6465
12	50	Unbiased-50k	133.94	135.82	1.8836
13	50	Unbiased-50k	138.36	138.8	0.4389
14	50	Unbiased-50k	140.07	140.89	0.8155
16	50	Unbiased-50k	140.48	142.78	2.3036
17	60	Biased-50k	143.22	144.5	1.2782
18	60	Biased-50k	127.7	129.16	1.4627
19	60	Biased-50k	140.64	141.35	0.7175
20	60	Biased-50k	135.8	138.73	2.9293
21	60	Biased-50k	128.45	128.87	0.4162
24	100	Unbiased-100k	128.63	129.51	0.8782
25	100	Unbiased-100k	140.48	141.02	0.5403
26	100	Unbiased-100k	130.1	133.88	3.7849
27	100	Unbiased-100k	129.04	130.18	1.1388
28	100	Unbiased-100k	133.08	136.19	3.1105
29	110	Biased-100k	138.67	142.1	3.4316
30	110	Biased-100k	145.17	147.48	2.3114
31	110	Biased-100k	131.26	133.8	2.5348
32	110	Biased-100k	134.81	152.99	18.181
34	110	Biased-100k	134.69	138.19	3.5037

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	140.53	142.14	145.04	2.5186	140.72	142.41	145.53	2.6977	0.1625	0.27973	0.4877	0.18059
50	133.94	137.8	140.48	2.7529	135.82	139.42	142.78	2.6076	0.4389	1.6176	2.6465	0.95298
60	127.7	135.16	143.22	6.9996	128.87	136.52	144.5	7.151	0.4162	1.3608	2.9293	0.97256
100	128.63	132.27	140.48	4.9113	129.51	134.16	141.02	4.7106	0.5403	1.8905	3.7849	1.4569
110	131.26	136.92	145.17	5.3049	133.8	142.91	152.99	7.5592	2.3114	5.9925	18.181	6.8341

Device Test: 38.12 EA_SOURCE(EA|SourceCurrent/COMP4/3/3///90.9/634//0///@EA_SOURCE)





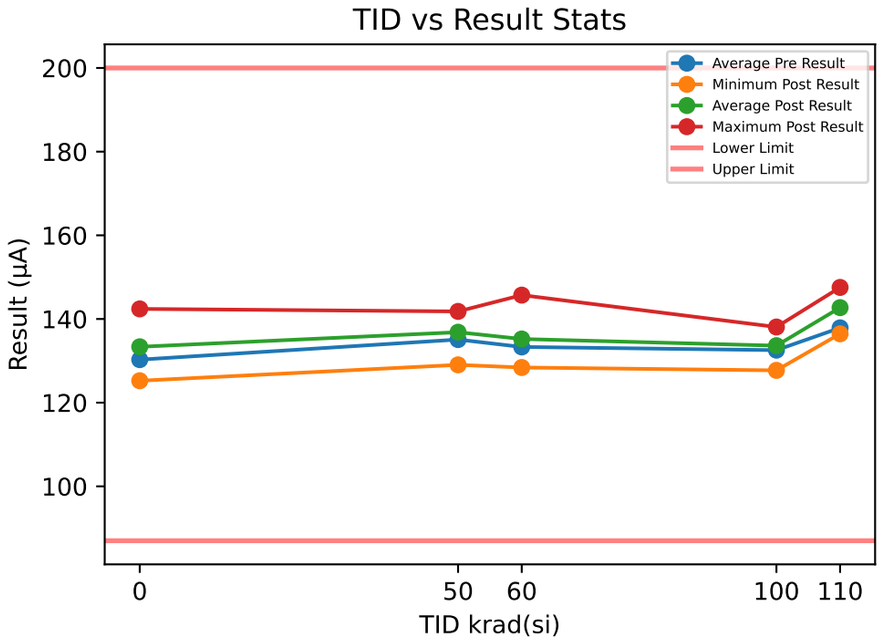
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

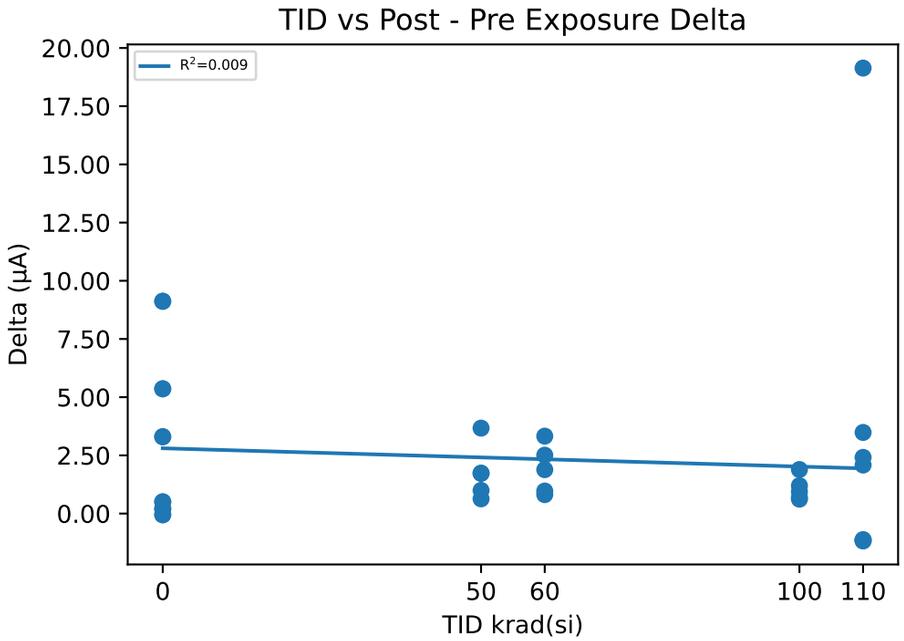
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	138.58	138.75	0.1755
2	0	CU2	130.37	130.37	0.0034
3	0	CU3	138.22	138.2	-0.0202
11	50	Unbiased-50k	131.52	133.7	2.1751
12	50	Unbiased-50k	137.32	140.34	3.0199
13	50	Unbiased-50k	127.53	127.3	-0.2243
14	50	Unbiased-50k	143.93	145.36	1.4282
16	50	Unbiased-50k	143.74	144.7	0.9604
17	60	Biased-50k	141.84	143.47	1.6345
18	60	Biased-50k	147.33	148.7	1.3753
19	60	Biased-50k	135.39	137.12	1.7273
20	60	Biased-50k	140.75	143.93	3.1734
21	60	Biased-50k	133.46	134.86	1.4004
24	100	Unbiased-100k	131.91	133.5	1.589
25	100	Unbiased-100k	125.87	125.68	-0.1919
26	100	Unbiased-100k	122.83	123.38	0.5491
27	100	Unbiased-100k	126.2	127.94	1.7351
28	100	Unbiased-100k	135.48	139.61	4.1258
29	110	Biased-100k	125.2	128.61	3.4057
30	110	Biased-100k	138.33	140.41	2.0783
31	110	Biased-100k	135.16	135.49	0.3376
32	110	Biased-100k	137.13	140.36	3.2342
34	110	Biased-100k	147.25	150.38	3.1284

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	130.37	135.72	138.58	4.6404	130.37	135.77	138.75	4.688	-0.0202	0.0529	0.1755	0.10683
50	127.53	136.81	143.93	7.2988	127.3	138.28	145.36	7.6981	-0.2243	1.4719	3.0199	1.2279
60	133.46	139.75	147.33	5.5088	134.86	141.62	148.7	5.5884	1.3753	1.8622	3.1734	0.74827
100	122.83	128.46	135.48	5.1183	123.38	130.02	139.61	6.5459	-0.1919	1.5614	4.1258	1.636
110	125.2	136.61	147.25	7.8855	128.61	139.05	150.38	7.9627	0.3376	2.4368	3.4057	1.2834

Device Test: 38.13 EA_SINK(EA|SinkCurrent/COMP1/3/3///90.9/634//0///@EA_SINK)





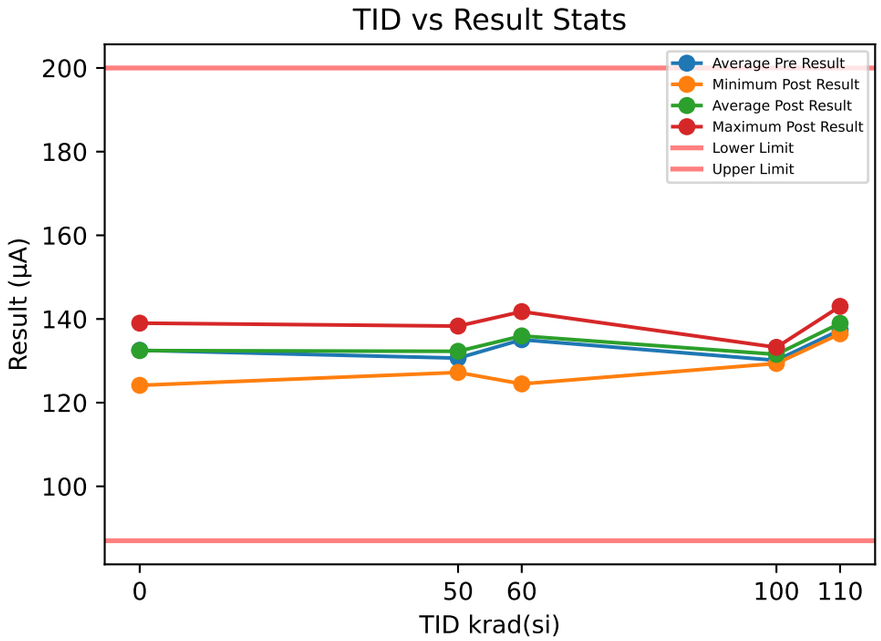
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

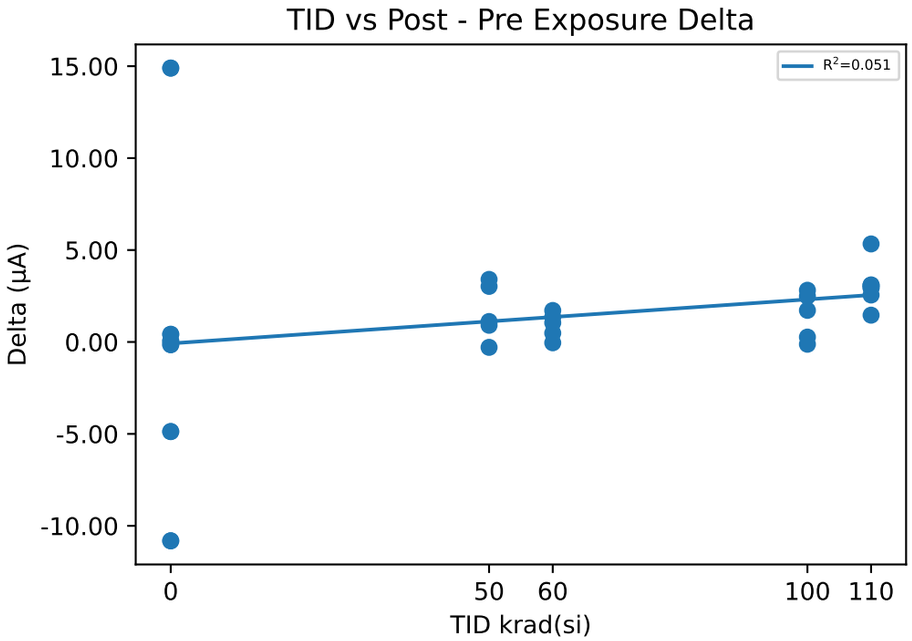
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	137.05	137.56	0.5031
2	0	CU2	128.5	128.7	0.2028
3	0	CU3	125.29	125.24	-0.0508
11	50	Unbiased-50k	128.4	129.04	0.6325
12	50	Unbiased-50k	138.67	139.66	0.9949
13	50	Unbiased-50k	138.14	141.81	3.6699
14	50	Unbiased-50k	136.91	138.64	1.7266
16	50	Unbiased-50k	133.3	135.04	1.7362
17	60	Biased-50k	135.08	135.89	0.8137
18	60	Biased-50k	127.25	129.14	1.8858
19	60	Biased-50k	135.97	136.94	0.9682
20	60	Biased-50k	142.38	145.71	3.3256
21	60	Biased-50k	125.9	128.4	2.5075
24	100	Unbiased-100k	137.39	138.08	0.691
25	100	Unbiased-100k	134.93	136.13	1.1986
26	100	Unbiased-100k	127.37	129.26	1.8912
27	100	Unbiased-100k	127.1	127.72	0.6189
28	100	Unbiased-100k	135.97	136.91	0.9388
29	110	Biased-100k	134.37	136.46	2.0843
30	110	Biased-100k	142.22	145.7	3.4847
31	110	Biased-100k	141.15	143.56	2.414
32	110	Biased-100k	128.41	147.54	19.137
34	110	Biased-100k	143.26	142.13	-1.126

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	125.29	130.28	137.05	6.0803	125.24	130.5	137.56	6.3519	-0.0508	0.21837	0.5031	0.27728
50	128.4	135.08	138.67	4.2814	129.04	136.84	141.81	5.001	0.6325	1.752	3.6699	1.1732
60	125.9	133.32	142.38	6.7851	128.4	135.22	145.71	7.0146	0.8137	1.9002	3.3256	1.0547
100	127.1	132.55	137.39	4.9326	127.72	133.62	138.08	4.7654	0.6189	1.0677	1.8912	0.51362
110	128.41	137.88	143.26	6.3337	136.46	143.08	147.54	4.2364	-1.126	5.1989	19.137	7.9794

Device Test: 38.14 EA_SINK(EA|SinkCurrent/COMP2/3/3///90.9/634//0///@EA_SINK)





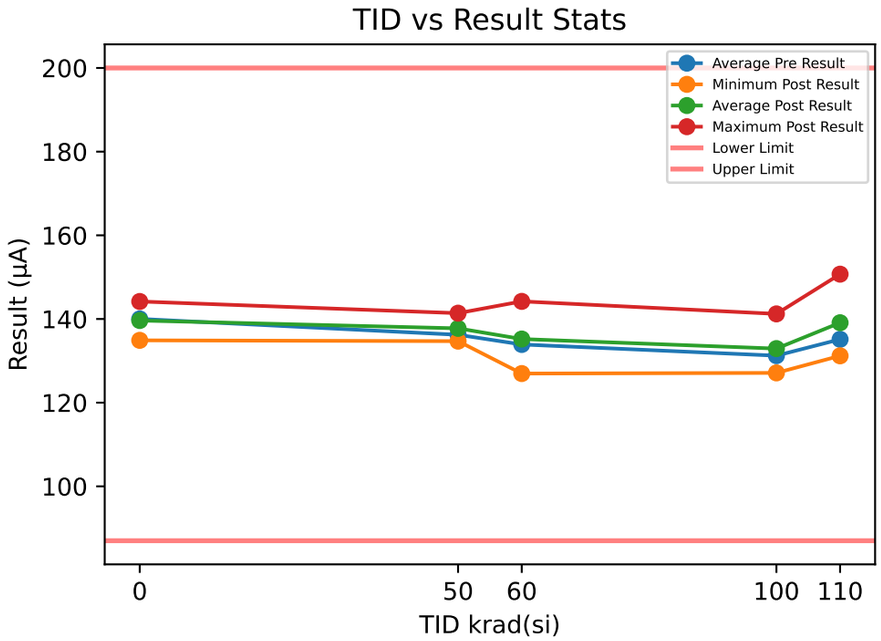
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

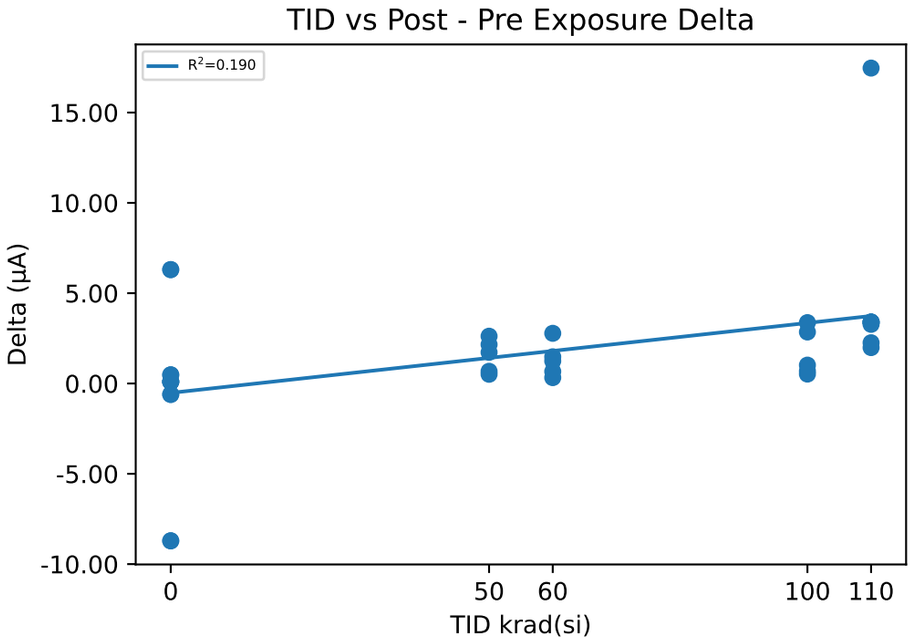
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	138.5	138.92	0.4167
2	0	CU2	124.11	124.16	0.0528
3	0	CU3	134.96	134.81	-0.146
11	50	Unbiased-50k	126.3	127.42	1.1128
12	50	Unbiased-50k	127.51	127.22	-0.2922
13	50	Unbiased-50k	135.28	138.3	3.0233
14	50	Unbiased-50k	131.35	134.75	3.4033
16	50	Unbiased-50k	132.78	133.69	0.9082
17	60	Biased-50k	139.87	141.58	1.7129
18	60	Biased-50k	124	124.48	0.4817
19	60	Biased-50k	135.78	137.13	1.3541
20	60	Biased-50k	141.81	141.76	-0.045
21	60	Biased-50k	133.8	134.84	1.0433
24	100	Unbiased-100k	131	130.88	-0.1234
25	100	Unbiased-100k	130.41	133.22	2.8142
26	100	Unbiased-100k	132.35	132.61	0.266
27	100	Unbiased-100k	126.88	129.37	2.4862
28	100	Unbiased-100k	129.91	131.62	1.7186
29	110	Biased-100k	140.41	141.87	1.458
30	110	Biased-100k	137.09	139.65	2.5545
31	110	Biased-100k	138.09	141.15	3.065
32	110	Biased-100k	137.68	143.02	5.332
34	110	Biased-100k	133.51	136.61	3.0977

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	124.11	132.52	138.5	7.4995	124.16	132.63	138.92	7.6167	-0.146	0.10783	0.4167	0.28536
50	126.3	130.65	135.28	3.7155	127.22	132.28	138.3	4.8385	-0.2922	1.6311	3.4033	1.5467
60	124	135.05	141.81	6.946	124.48	135.96	141.76	7.063	-0.045	0.9094	1.7129	0.69913
100	126.88	130.11	132.35	2.0219	129.37	131.54	133.22	1.5115	-0.1234	1.4323	2.8142	1.3118
110	133.51	137.36	140.41	2.4922	136.61	140.46	143.02	2.4753	1.458	3.1014	5.332	1.4122

Device Test: 38.15 EA_SINK(EA|SinkCurrent/COMP3/3/3///90.9/634//0///@EA_SINK)





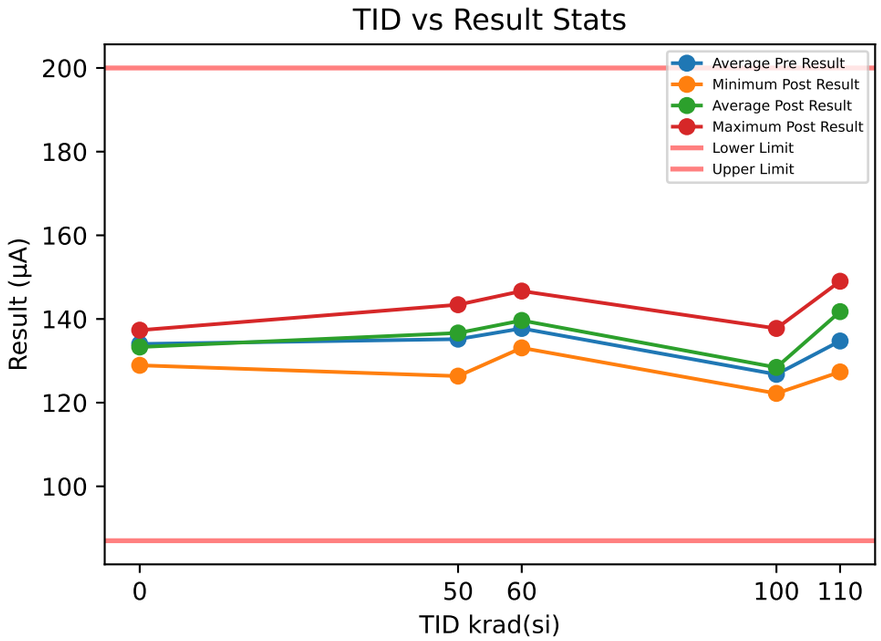
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

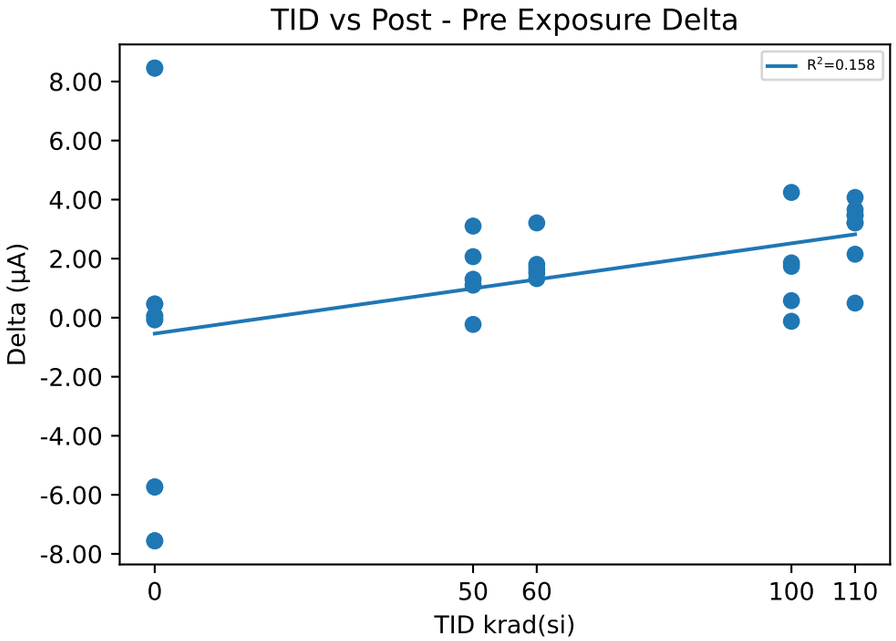
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	143.61	144.09	0.4785
2	0	CU2	137.88	137.97	0.0949
3	0	CU3	138.58	138.68	0.1013
11	50	Unbiased-50k	134.46	137.08	2.6183
12	50	Unbiased-50k	132.98	134.7	1.7253
13	50	Unbiased-50k	136.29	136.8	0.5099
14	50	Unbiased-50k	138.16	138.84	0.6758
16	50	Unbiased-50k	139.23	141.39	2.158
17	60	Biased-50k	142.96	144.21	1.245
18	60	Biased-50k	127.07	128.55	1.4776
19	60	Biased-50k	138.2	138.86	0.6673
20	60	Biased-50k	134.69	137.47	2.7781
21	60	Biased-50k	126.63	126.96	0.3251
24	100	Unbiased-100k	126.43	127.11	0.6875
25	100	Unbiased-100k	140.7	141.22	0.5211
26	100	Unbiased-100k	129.11	132.48	3.3704
27	100	Unbiased-100k	127.56	128.58	1.017
28	100	Unbiased-100k	132.38	135.23	2.8503
29	110	Biased-100k	137.49	140.76	3.2751
30	110	Biased-100k	143.18	145.17	1.9881
31	110	Biased-100k	128.94	131.2	2.2561
32	110	Biased-100k	133.25	150.71	17.463
34	110	Biased-100k	132.86	136.26	3.4021

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	137.88	140.02	143.61	3.1244	137.97	140.25	144.09	3.3431	0.0949	0.2249	0.4785	0.21965
50	132.98	136.22	139.23	2.5721	134.7	137.76	141.39	2.5037	0.5099	1.5375	2.6183	0.92018
60	126.63	133.91	142.96	7.0824	126.96	135.21	144.21	7.2775	0.3251	1.2986	2.7781	0.94473
100	126.43	131.23	140.7	5.7437	127.11	132.92	141.22	5.6332	0.5211	1.6893	3.3704	1.3223
110	128.94	135.14	143.18	5.4166	131.2	140.82	150.71	7.5863	1.9881	5.6768	17.463	6.6174

Device Test: 38.16 EA_SINK(EA|SinkCurrent/COMP4/3/3///90.9/634//0///@EA_SINK)





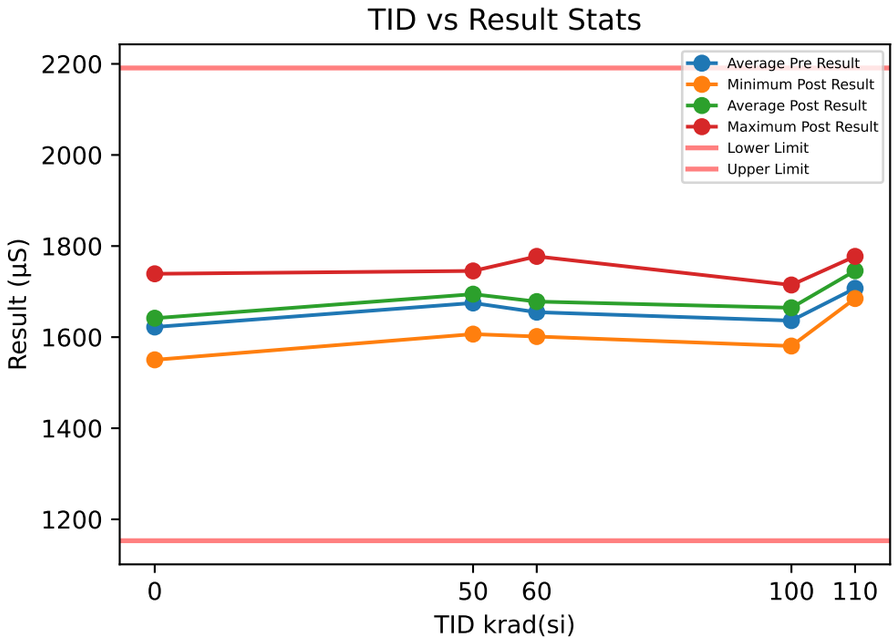
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

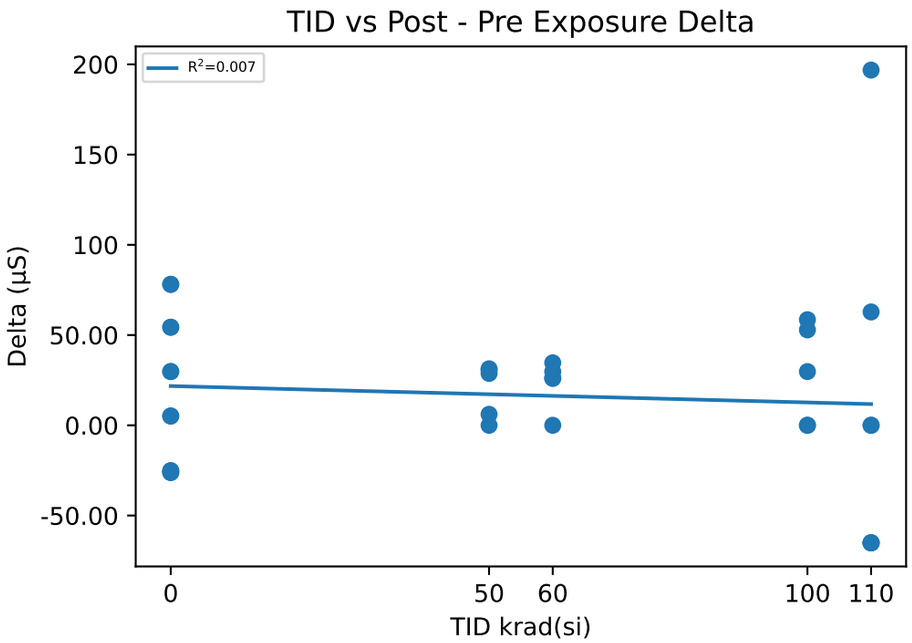
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	136.74	137.21	0.4622
2	0	CU2	128.87	128.93	0.0591
3	0	CU3	136.48	136.41	-0.0681
11	50	Unbiased-50k	130.18	132.24	2.067
12	50	Unbiased-50k	135.73	138.83	3.1031
13	50	Unbiased-50k	126.57	126.35	-0.2278
14	50	Unbiased-50k	142.11	143.41	1.3025
16	50	Unbiased-50k	141.32	142.42	1.1025
17	60	Biased-50k	139.88	141.55	1.6652
18	60	Biased-50k	145.16	146.67	1.5139
19	60	Biased-50k	132.94	134.75	1.8051
20	60	Biased-50k	138.95	142.16	3.2104
21	60	Biased-50k	131.77	133.1	1.3232
24	100	Unbiased-100k	129.95	131.69	1.7382
25	100	Unbiased-100k	123.51	123.39	-0.1215
26	100	Unbiased-100k	121.64	122.21	0.5763
27	100	Unbiased-100k	125.23	127.09	1.8556
28	100	Unbiased-100k	133.5	137.74	4.2428
29	110	Biased-100k	123.68	127.34	3.6598
30	110	Biased-100k	137.05	139.2	2.1499
31	110	Biased-100k	132.96	133.45	0.4938
32	110	Biased-100k	134.44	138.52	4.0731
34	110	Biased-100k	145.55	149.02	3.4715

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	128.87	134.03	136.74	4.4724	128.93	134.18	137.21	4.5673	-0.0681	0.15107	0.4622	0.27685
50	126.57	135.18	142.11	6.8016	126.35	136.65	143.41	7.2342	-0.2278	1.4695	3.1031	1.2318
60	131.77	137.74	145.16	5.4705	133.1	139.65	146.67	5.6167	1.3232	1.9036	3.2104	0.75216
100	121.64	126.77	133.5	4.865	122.21	128.42	137.74	6.3857	-0.1215	1.6583	4.2428	1.6631
110	123.68	134.74	145.55	7.8686	127.34	137.51	149.02	8.0026	0.4938	2.7696	4.0731	1.4618

Device Test: 38.17 EA_GM_25C(EA|Transconductance/VSNS1/3/3///90.9/634//0///@EA_GM_25C)





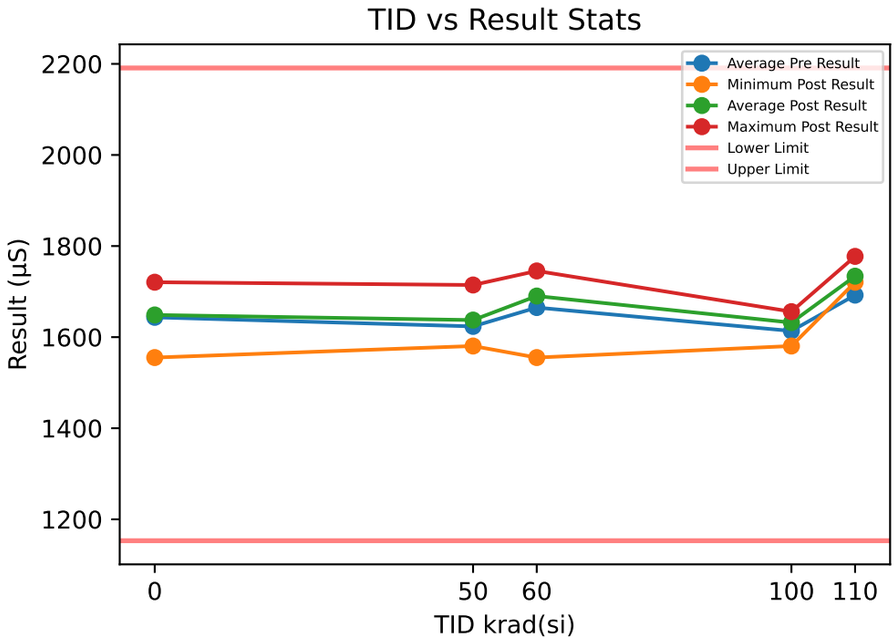
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

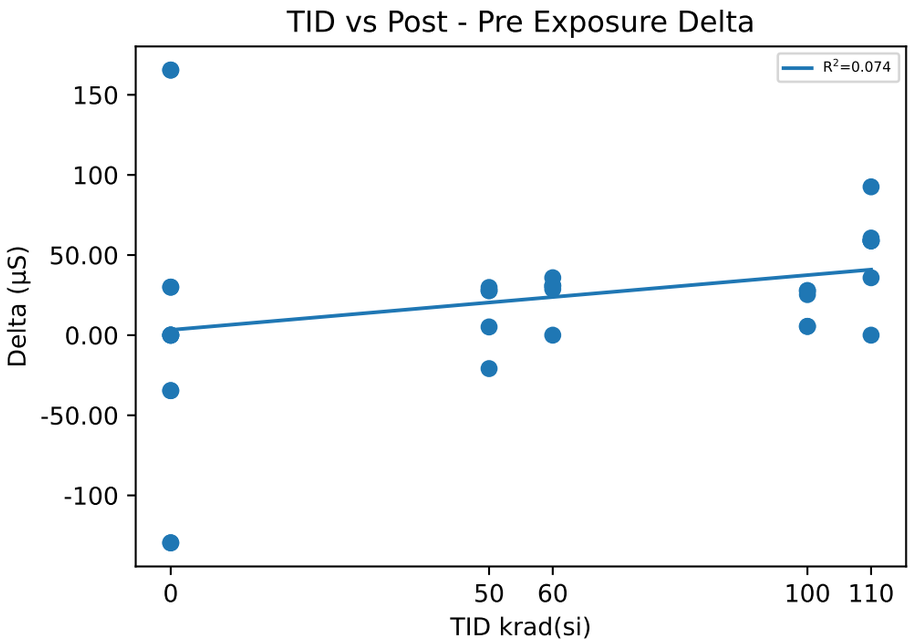
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1684.7	1714.5	29.766
2	0	CU2	1606.6	1580.5	-26.167
3	0	CU3	1575.3	1550.2	-25.165
11	50	Unbiased-50k	1575.3	1606.6	31.298
12	50	Unbiased-50k	1714.5	1745.3	30.836
13	50	Unbiased-50k	1714.5	1714.5	0
14	50	Unbiased-50k	1714.5	1720.6	6.0798
16	50	Unbiased-50k	1656	1684.7	28.75
17	60	Biased-50k	1656	1690.6	34.62
18	60	Biased-50k	1580.5	1606.6	26.167
19	60	Biased-50k	1684.7	1714.5	29.766
20	60	Biased-50k	1777.3	1777.3	0
21	60	Biased-50k	1575.3	1601.3	25.996
24	100	Unbiased-100k	1684.7	1714.5	29.766
25	100	Unbiased-100k	1684.7	1684.7	0
26	100	Unbiased-100k	1575.3	1628.2	52.864
27	100	Unbiased-100k	1580.5	1580.5	0
28	100	Unbiased-100k	1656	1714.5	58.515
29	110	Biased-100k	1684.7	1684.7	0
30	110	Biased-100k	1714.5	1777.3	62.802
31	110	Biased-100k	1745.3	1745.3	0
32	110	Biased-100k	1580.5	1777.3	196.84
34	110	Biased-100k	1810.5	1745.3	-65.125

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1622.2	1684.7	56.343	1550.2	1615.1	1714.5	87.452	-26.167	-7.1887	29.766	32.007
50	1575.3	1675	1714.5	61.187	1606.6	1694.4	1745.3	53.573	0	19.393	31.298	15.113
60	1575.3	1654.8	1777.3	83.283	1601.3	1678.1	1777.3	74.705	0	23.31	34.62	13.494
100	1575.3	1636.3	1684.7	54.574	1580.5	1664.5	1714.5	58.713	0	28.229	58.515	27.93
110	1580.5	1707.1	1810.5	84.759	1684.7	1746	1777.3	37.796	-65.125	38.903	196.84	99.2

Device Test: 38.18 EA_GM_25C(EA|Transconductance/VSNS2/3/3///90.9/634//0///@EA_GM_25C)





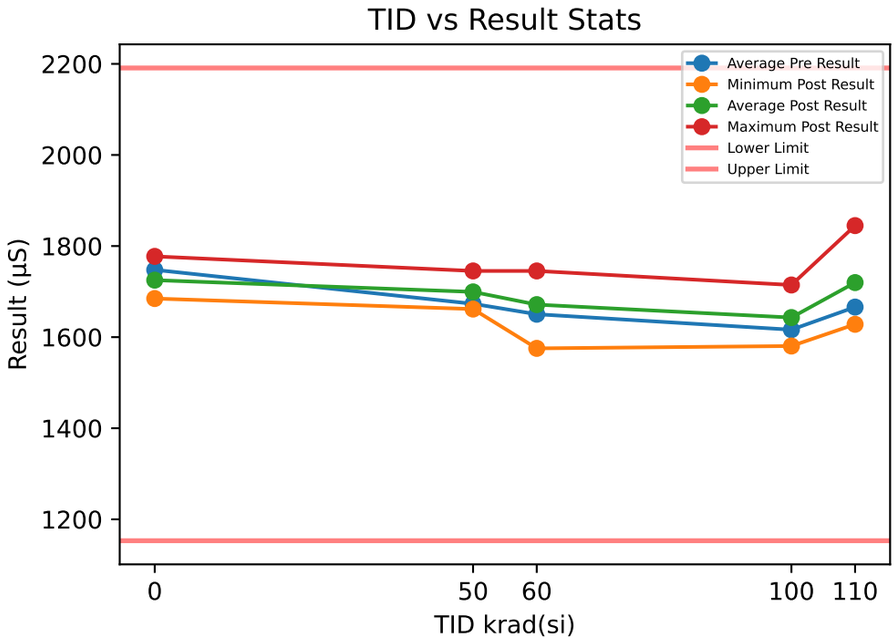
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

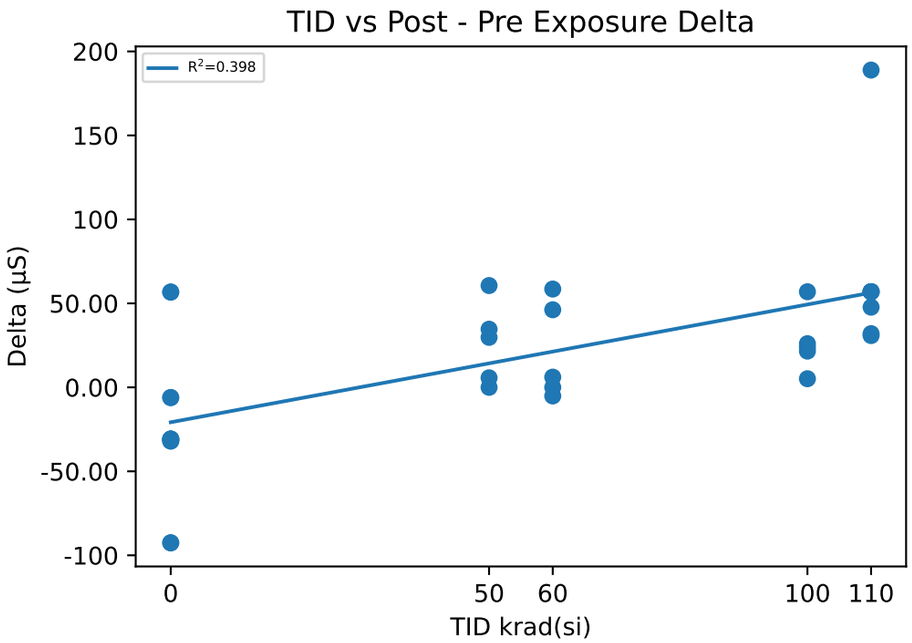
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1690.6	1720.6	29.975
2	0	CU2	1555.1	1555.1	0
3	0	CU3	1684.7	1684.7	0
11	50	Unbiased-50k	1575.3	1580.5	5.1314
12	50	Unbiased-50k	1601.3	1580.5	-20.864
13	50	Unbiased-50k	1684.7	1714.5	29.766
14	50	Unbiased-50k	1628.2	1656	27.785
16	50	Unbiased-50k	1628.2	1656	27.785
17	60	Biased-50k	1714.5	1745.3	30.836
18	60	Biased-50k	1555.1	1555.1	0
19	60	Biased-50k	1684.7	1720.6	35.845
20	60	Biased-50k	1714.5	1745.3	30.836
21	60	Biased-50k	1656	1684.7	28.75
24	100	Unbiased-100k	1628.2	1633.7	5.4821
25	100	Unbiased-100k	1628.2	1656	27.785
26	100	Unbiased-100k	1628.2	1633.7	5.4821
27	100	Unbiased-100k	1555.1	1580.5	25.328
28	100	Unbiased-100k	1628.2	1656	27.785
29	110	Biased-100k	1745.3	1745.3	0
30	110	Biased-100k	1684.7	1720.6	35.845
31	110	Biased-100k	1684.7	1745.3	60.602
32	110	Biased-100k	1684.7	1777.3	92.568
34	110	Biased-100k	1661.7	1720.6	58.924

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1555.1	1643.5	1690.6	76.573	1555.1	1653.5	1720.6	87.035	0	9.9918	29.975	17.306
50	1575.3	1623.6	1684.7	40.636	1580.5	1637.5	1714.5	57.267	-20.864	13.921	29.766	21.925
60	1555.1	1665	1714.5	66.032	1555.1	1690.2	1745.3	79.489	0	25.254	35.845	14.357
100	1555.1	1613.6	1628.2	32.674	1580.5	1632	1656	30.87	5.4821	18.372	27.785	11.81
110	1661.7	1692.2	1745.3	31.319	1720.6	1741.8	1777.3	23.377	0	49.588	92.568	34.291

Device Test: 38.19 EA_GM_25C(EA|Transconductance/VSNS3/3/3///90.9/634//0///@EA_GM_25C)





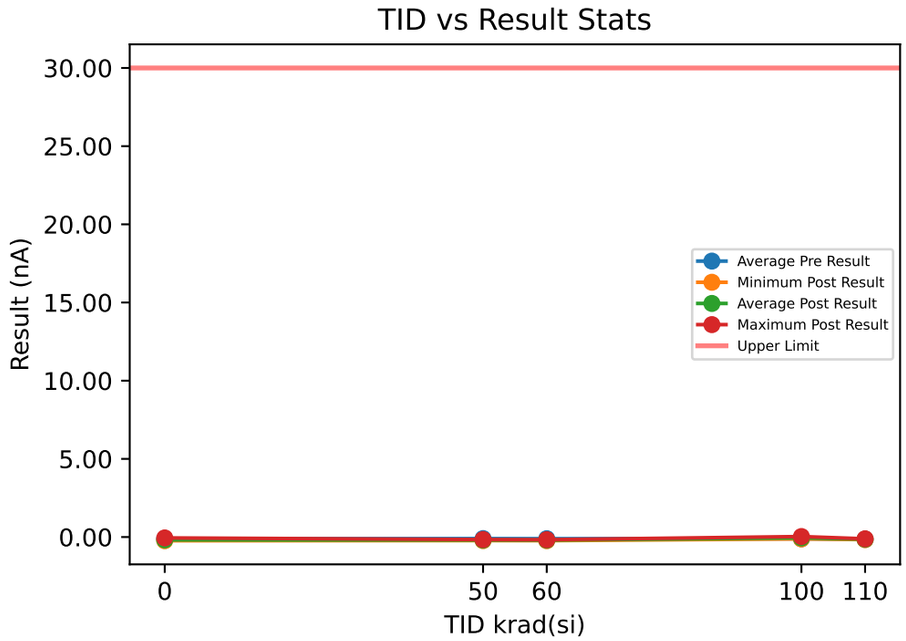
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

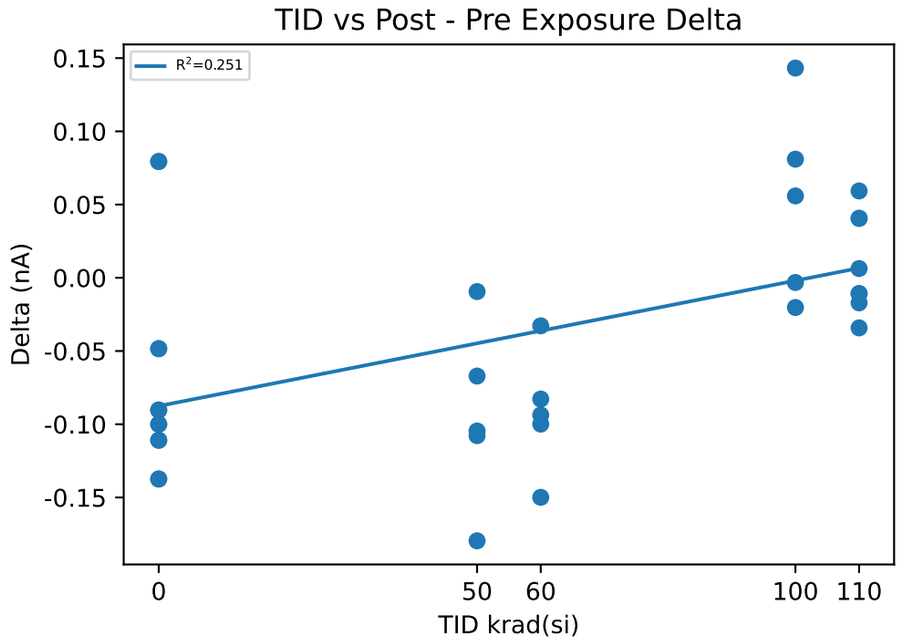
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1777.3	1745.3	-31.966
2	0	CU2	1720.6	1714.5	-6.0798
3	0	CU3	1745.3	1714.5	-30.836
11	50	Unbiased-50k	1656	1690.6	34.62
12	50	Unbiased-50k	1656	1661.7	5.6712
13	50	Unbiased-50k	1684.7	1684.7	0
14	50	Unbiased-50k	1684.7	1714.5	29.766
16	50	Unbiased-50k	1684.7	1745.3	60.602
17	60	Biased-50k	1745.3	1745.3	0
18	60	Biased-50k	1555.1	1601.3	46.192
19	60	Biased-50k	1714.5	1720.6	6.0798
20	60	Biased-50k	1656	1714.5	58.515
21	60	Biased-50k	1580.5	1575.3	-5.1314
24	100	Unbiased-100k	1575.3	1580.5	5.1314
25	100	Unbiased-100k	1690.6	1714.5	23.895
26	100	Unbiased-100k	1606.6	1628.2	21.566
27	100	Unbiased-100k	1575.3	1601.3	25.996
28	100	Unbiased-100k	1633.7	1690.6	56.923
29	110	Biased-100k	1714.5	1745.3	30.836
30	110	Biased-100k	1745.3	1777.3	31.966
31	110	Biased-100k	1580.5	1628.2	47.732
32	110	Biased-100k	1656	1844.9	188.9
34	110	Biased-100k	1633.7	1690.6	56.923

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1720.6	1747.7	1777.3	28.438	1714.5	1724.8	1745.3	17.803	-31.966	-22.961	-6.0798	14.63
50	1656	1673.2	1684.7	15.747	1661.7	1699.4	1745.3	31.84	0	26.132	60.602	24.367
60	1555.1	1650.3	1745.3	82.338	1575.3	1671.4	1745.3	77.267	-5.1314	21.131	58.515	29.105
100	1575.3	1616.3	1690.6	48.148	1580.5	1643	1714.5	57.542	5.1314	26.702	56.923	18.797
110	1580.5	1666	1745.3	65.397	1628.2	1737.3	1844.9	82.646	30.836	71.271	188.9	66.662

Device Test: 38.2 IVSNS_LKG(EA|Leakage/VSNS2/3/3///90.9/634//0///@IVSNS_LKG)





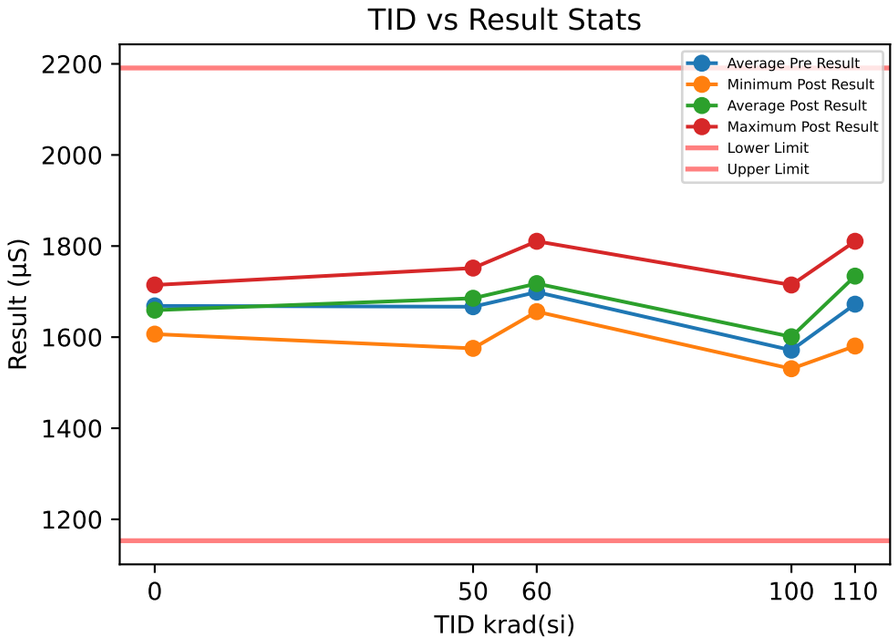
Test Results (Upper Limit = 30.0 (nA))

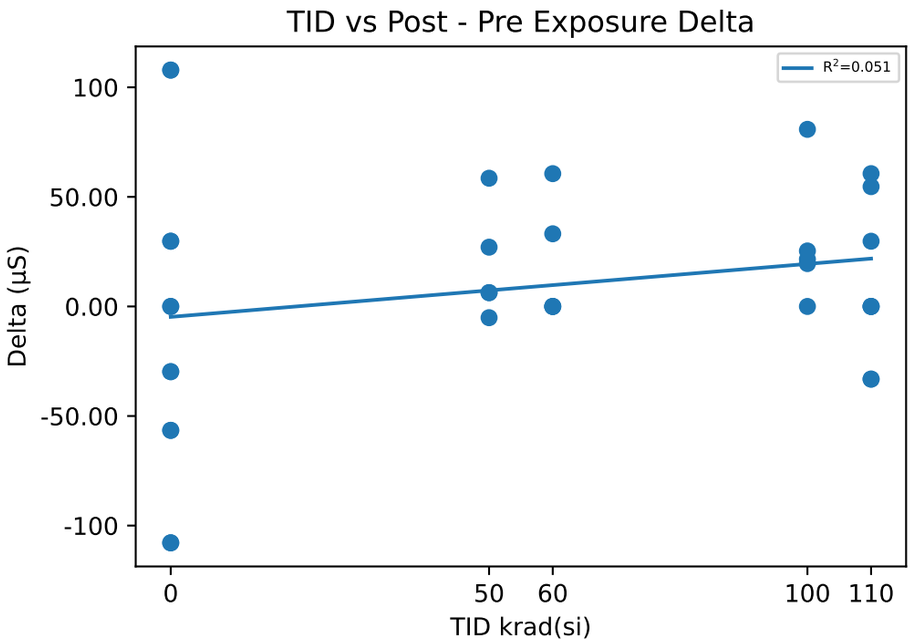
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.121	-0.2319	-0.1109
2	0	CU2	-0.135	-0.235	-0.1
3	0	CU3	-0.0835	-0.2209	-0.1374
11	50	Unbiased-50k	-0.0882	-0.1928	-0.1046
12	50	Unbiased-50k	-0.0476	-0.2272	-0.1796
13	50	Unbiased-50k	-0.1163	-0.2241	-0.1078
14	50	Unbiased-50k	-0.0929	-0.16	-0.0671
16	50	Unbiased-50k	-0.1522	-0.1616	-0.0094
17	60	Biased-50k	-0.0929	-0.1866	-0.0937
18	60	Biased-50k	-0.1101	-0.21	-0.0999
19	60	Biased-50k	-0.1491	-0.2319	-0.0828
20	60	Biased-50k	-0.0195	-0.1694	-0.1499
21	60	Biased-50k	-0.1569	-0.1897	-0.0328
24	100	Unbiased-100k	-0.0866	-0.0307	0.0559
25	100	Unbiased-100k	-0.1116	0.0316	0.1432
26	100	Unbiased-100k	-0.1147	-0.1179	-0.0032
27	100	Unbiased-100k	-0.1397	-0.0587	0.081
28	100	Unbiased-100k	-0.0726	-0.0929	-0.0203
29	110	Biased-100k	-0.1491	-0.1428	0.0063
30	110	Biased-100k	-0.1319	-0.1661	-0.0342
31	110	Biased-100k	-0.1772	-0.1179	0.0593
32	110	Biased-100k	-0.1194	-0.1365	-0.0171
34	110	Biased-100k	-0.1522	-0.163	-0.0108

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.135	-0.11317	-0.0835	0.026629	-0.235	-0.22927	-0.2209	0.0074097	-0.1374	-0.1161	-0.1	0.019235
50	-0.1522	-0.09944	-0.0476	0.038485	-0.2272	-0.19314	-0.16	0.032449	-0.1796	-0.0937	-0.0094	0.062271
60	-0.1569	-0.1057	-0.0195	0.055042	-0.2319	-0.19752	-0.1694	0.024025	-0.1499	-0.09182	-0.0328	0.041853
100	-0.1397	-0.10504	-0.0726	0.026125	-0.1179	-0.05372	0.0316	0.05807	-0.0203	0.05132	0.1432	0.066041
110	-0.1772	-0.14596	-0.1194	0.021954	-0.1661	-0.14526	-0.1179	0.019877	-0.0342	0.0007	0.0593	0.03582

Device Test: 38.20 EA_GM_25C(EA|Transconductance/VSNS4/3/3///90.9/634//0///@EA_GM_25C)





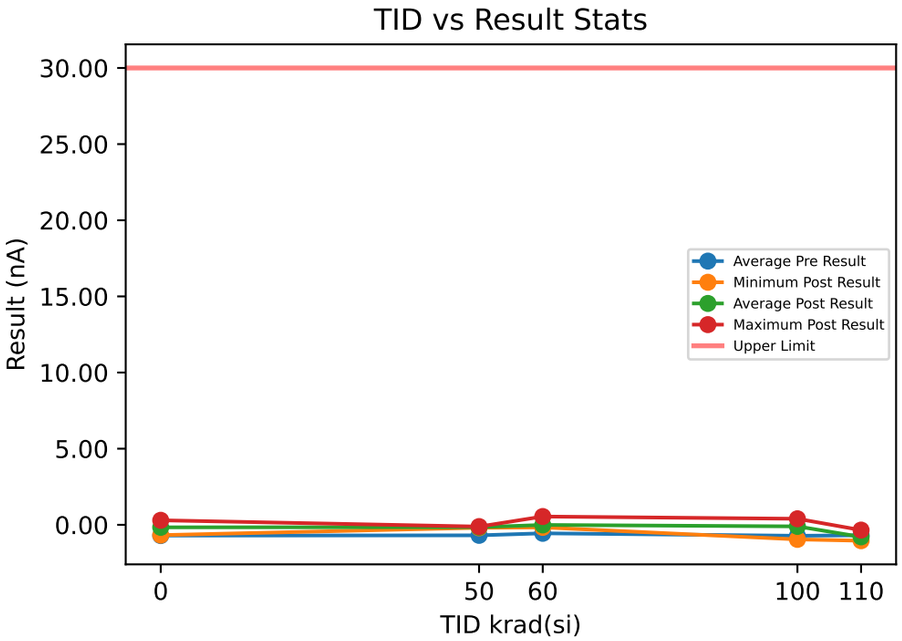
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

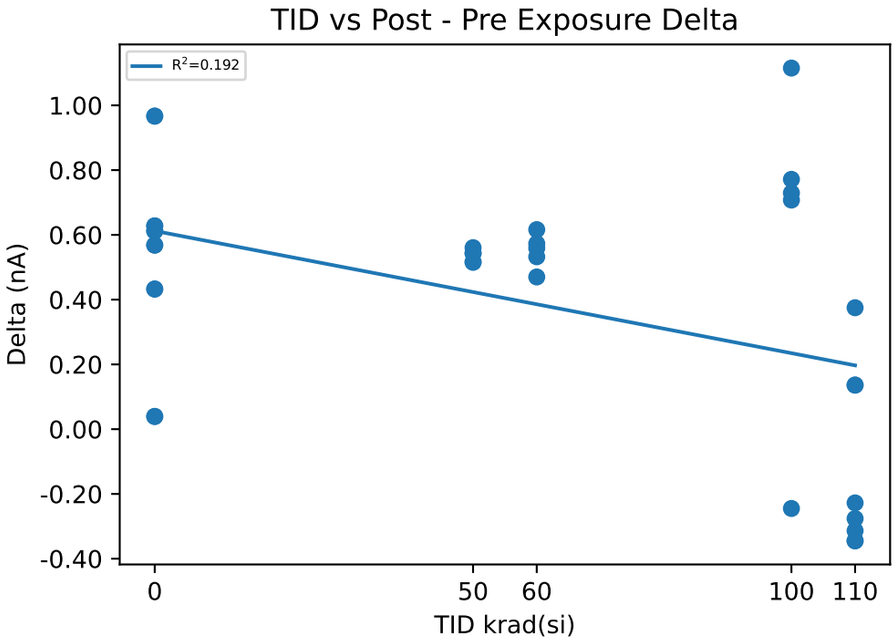
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1684.7	1714.5	29.766
2	0	CU2	1606.6	1606.6	0
3	0	CU3	1714.5	1684.7	-29.766
11	50	Unbiased-50k	1606.6	1633.7	27.048
12	50	Unbiased-50k	1656	1714.5	58.515
13	50	Unbiased-50k	1580.5	1575.3	-5.1314
14	50	Unbiased-50k	1745.3	1751.6	6.3009
16	50	Unbiased-50k	1745.3	1751.6	6.3009
17	60	Biased-50k	1714.5	1714.5	0
18	60	Biased-50k	1777.3	1810.5	33.159
19	60	Biased-50k	1661.7	1661.7	0
20	60	Biased-50k	1684.7	1745.3	60.602
21	60	Biased-50k	1656	1656	0
24	100	Unbiased-100k	1606.6	1628.2	21.566
25	100	Unbiased-100k	1530.6	1550.2	19.561
26	100	Unbiased-100k	1530.6	1530.6	0
27	100	Unbiased-100k	1555.1	1580.5	25.328
28	100	Unbiased-100k	1633.7	1714.5	80.818
29	110	Biased-100k	1525.8	1580.5	54.67
30	110	Biased-100k	1684.7	1745.3	60.602
31	110	Biased-100k	1656	1656	0
32	110	Biased-100k	1684.7	1714.5	29.766
34	110	Biased-100k	1810.5	1810.5	0

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1606.6	1668.6	1714.5	55.709	1606.6	1668.6	1714.5	55.709	-29.766	0	29.766	29.766
50	1580.5	1666.8	1745.3	76.691	1575.3	1685.4	1751.6	78.119	-5.1314	18.607	58.515	25.151
60	1656	1698.8	1777.3	49.548	1656	1717.6	1810.5	63.891	0	18.752	60.602	27.449
100	1530.6	1571.3	1633.7	46.67	1530.6	1600.8	1714.5	73.454	0	29.455	80.818	30.344
110	1525.8	1672.3	1810.5	101.4	1580.5	1701.4	1810.5	87.584	0	29.008	60.602	28.897

Device Test: 38.3 IVSNS_LKG(EA|Leakage/VSNS3/3/3///90.9/634//0///@IVSNS_LKG)





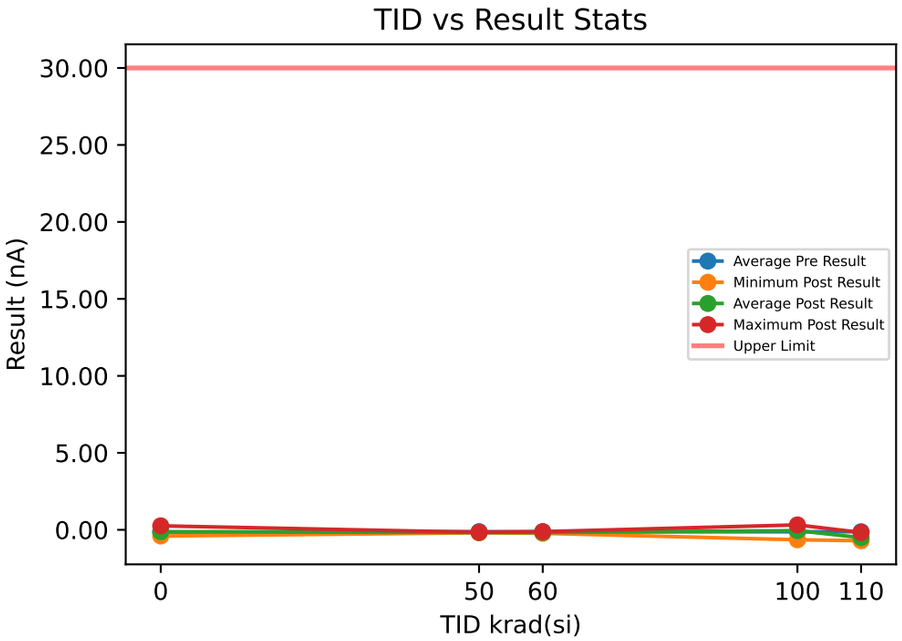
Test Results (Upper Limit = 30.0 (nA))

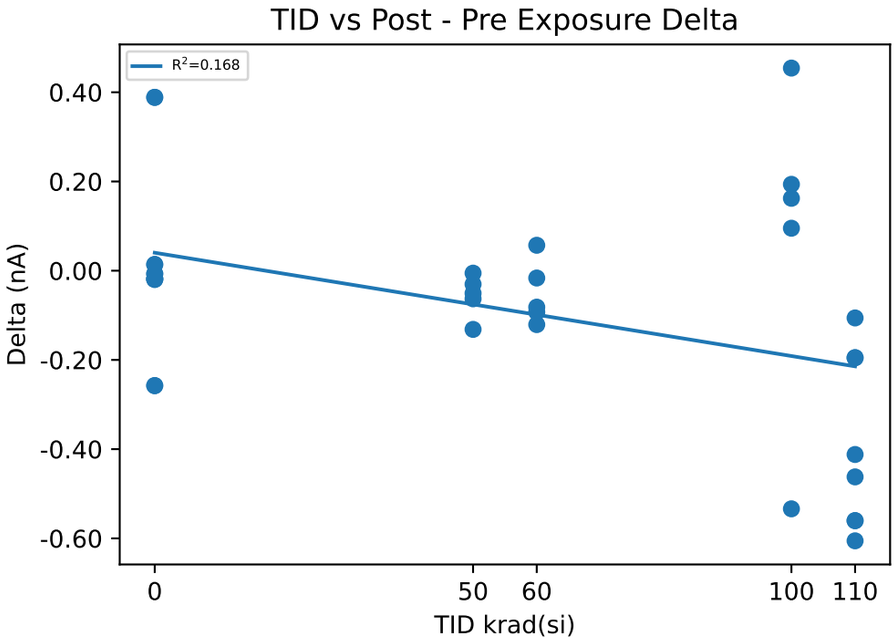
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.6694	-0.101	0.5684
2	0	CU2	-0.7318	-0.1041	0.6277
3	0	CU3	-0.7162	-0.1041	0.6121
11	50	Unbiased-50k	-0.7365	-0.1933	0.5432
12	50	Unbiased-50k	-0.6866	-0.1698	0.5168
13	50	Unbiased-50k	-0.6725	-0.1573	0.5152
14	50	Unbiased-50k	-0.6803	-0.137	0.5433
16	50	Unbiased-50k	-0.6756	-0.1151	0.5605
17	60	Biased-50k	-0.6834	-0.1104	0.573
18	60	Biased-50k	-0.6975	-0.1385	0.559
19	60	Biased-50k	-0.6975	-0.1651	0.5324
20	60	Biased-50k	-0.6382	-0.1682	0.47
21	60	Biased-50k	-0.0714	0.5448	0.6162
24	100	Unbiased-100k	-0.7178	0.3973	1.1151
25	100	Unbiased-100k	-0.6959	0.0756	0.7715
26	100	Unbiased-100k	-0.7115	-0.9564	-0.2449
27	100	Unbiased-100k	-0.7693	-0.0399	0.7294
28	100	Unbiased-100k	-0.699	0.0085	0.7075
29	110	Biased-100k	-0.7303	-1.0439	-0.3136
30	110	Biased-100k	-0.6819	-0.958	-0.2761
31	110	Biased-100k	-0.6335	-0.8612	-0.2277
32	110	Biased-100k	-0.7209	-0.3459	0.375
34	110	Biased-100k	-0.6741	-0.538	0.1361

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.7318	-0.7058	-0.6694	0.032474	-0.1041	-0.10307	-0.101	0.0017898	0.5684	0.60273	0.6277	0.03074
50	-0.7365	-0.6903	-0.6725	0.026368	-0.1933	-0.1545	-0.1151	0.030025	0.5152	0.5358	0.5605	0.019407
60	-0.6975	-0.5576	-0.0714	0.27288	-0.1682	-0.00748	0.5448	0.30962	0.47	0.55012	0.6162	0.054088
100	-0.7693	-0.7187	-0.6959	0.029669	-0.9564	-0.10298	0.3973	0.50668	-0.2449	0.61572	1.1151	0.50884
110	-0.7303	-0.68814	-0.6335	0.038962	-1.0439	-0.7494	-0.3459	0.29591	-0.3136	-0.06126	0.375	0.30282

Device Test: 38.4 IVSNS_LKG(EA|Leakage/VSNS4/3/3///90.9/634//0///@IVSNS_LKG)





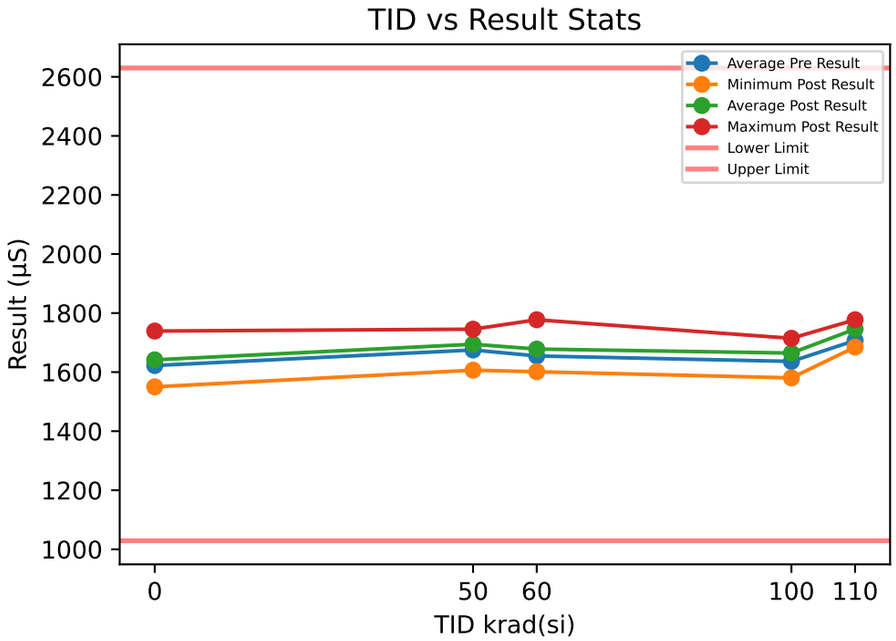
Test Results (Upper Limit = 30.0 (nA))

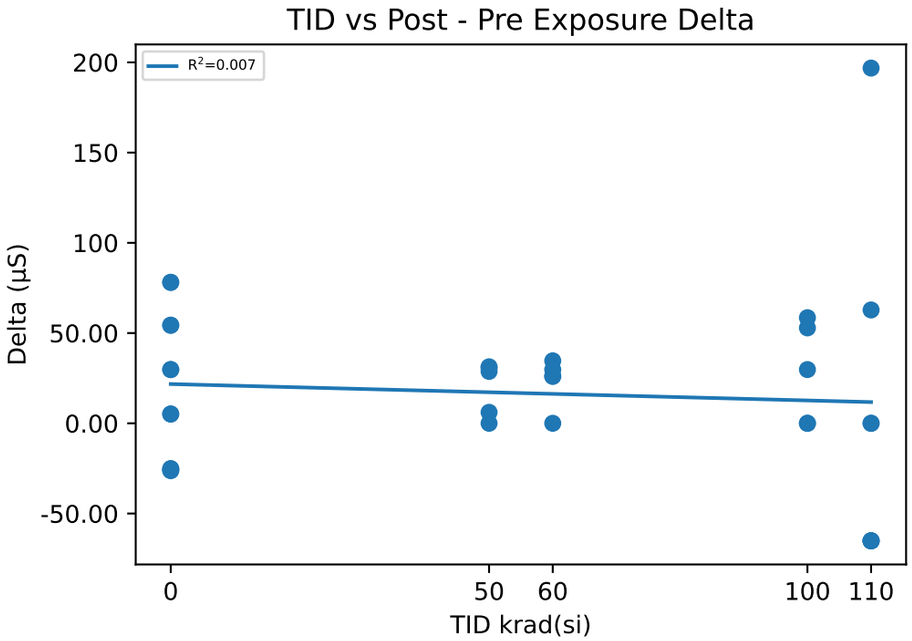
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.1304	-0.1373	-0.0069
2	0	CU2	-0.1553	-0.1732	-0.0179
3	0	CU3	-0.1444	-0.1639	-0.0195
11	50	Unbiased-50k	-0.1584	-0.1639	-0.0055
12	50	Unbiased-50k	-0.0619	-0.1935	-0.1316
13	50	Unbiased-50k	-0.132	-0.1623	-0.0303
14	50	Unbiased-50k	-0.104	-0.167	-0.063
16	50	Unbiased-50k	-0.1289	-0.1795	-0.0506
17	60	Biased-50k	-0.104	-0.1967	-0.0927
18	60	Biased-50k	-0.0931	-0.1748	-0.0817
19	60	Biased-50k	-0.1444	-0.1608	-0.0164
20	60	Biased-50k	-0.1055	-0.2263	-0.1208
21	60	Biased-50k	-0.1756	-0.1186	0.057
24	100	Unbiased-100k	-0.1351	0.3191	0.4542
25	100	Unbiased-100k	-0.1289	0.0647	0.1936
26	100	Unbiased-100k	-0.1133	-0.6471	-0.5338
27	100	Unbiased-100k	-0.1413	-0.0461	0.0952
28	100	Unbiased-100k	-0.1164	0.0459	0.1623
29	110	Biased-100k	-0.1024	-0.7079	-0.6055
30	110	Biased-100k	-0.188	-0.6502	-0.4622
31	110	Biased-100k	-0.1367	-0.5487	-0.412
32	110	Biased-100k	-0.0682	-0.1741	-0.1059
34	110	Biased-100k	-0.118	-0.3131	-0.1951

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1553	-0.14337	-0.1304	0.012482	-0.1732	-0.15813	-0.1373	0.018632	-0.0195	-0.014767	-0.0069	0.0068595
50	-0.1584	-0.11704	-0.0619	0.036351	-0.1935	-0.17324	-0.1623	0.013186	-0.1316	-0.0562	-0.0055	0.047445
60	-0.1756	-0.12452	-0.0931	0.034549	-0.2263	-0.17544	-0.1186	0.040262	-0.1208	-0.05092	0.057	0.07144
100	-0.1413	-0.127	-0.1133	0.011977	-0.6471	-0.0527	0.3191	0.35885	-0.5338	0.0743	0.4542	0.36624
110	-0.188	-0.12266	-0.0682	0.044341	-0.7079	-0.4788	-0.1741	0.22751	-0.6055	-0.35614	-0.1059	0.20316

Device Test: 38.5 EA_GM(EA|Transconductance/VSNS1/3/3///90.9/634//0///@EA_GM)





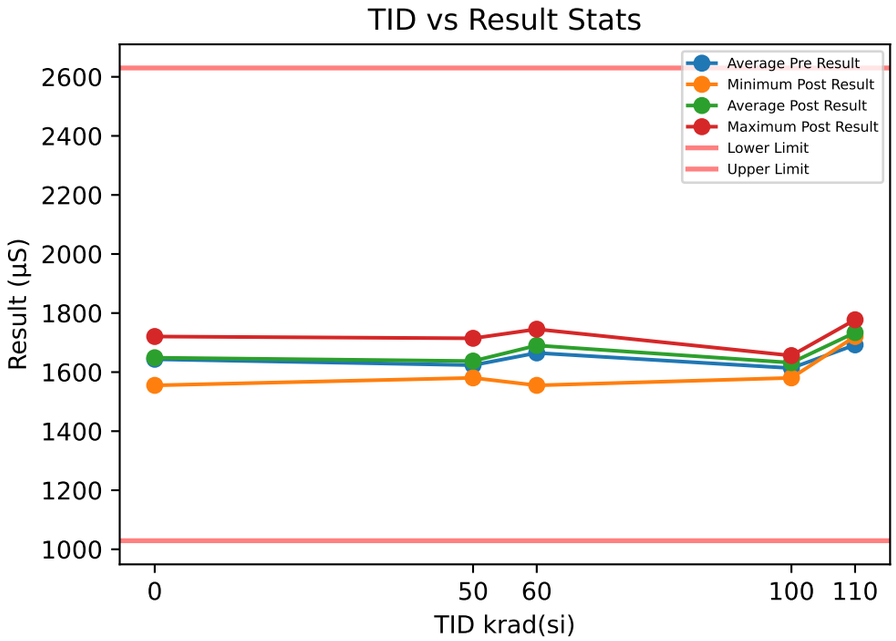
Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

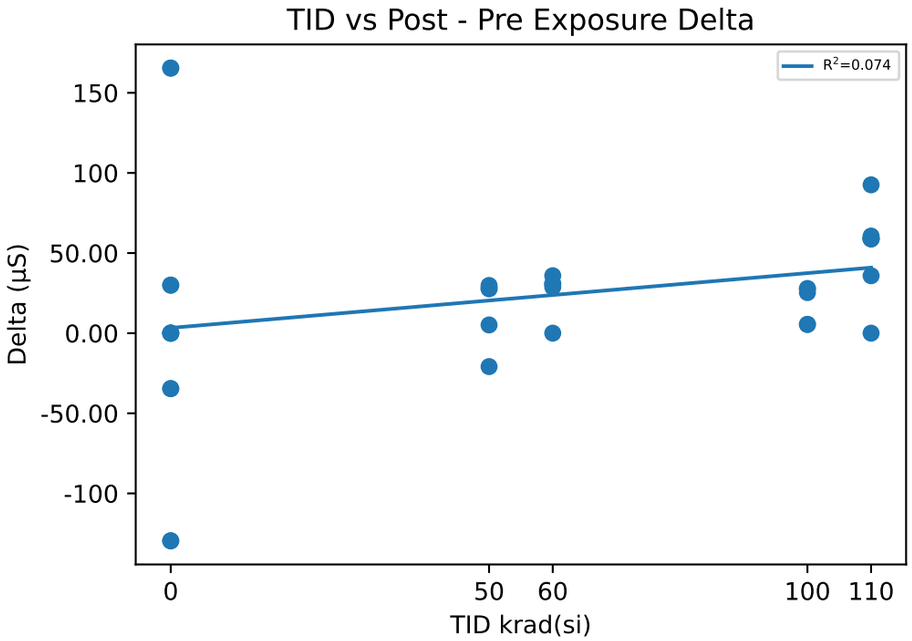
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1684.7	1714.5	29.766
2	0	CU2	1606.6	1580.5	-26.167
3	0	CU3	1575.3	1550.2	-25.165
11	50	Unbiased-50k	1575.3	1606.6	31.298
12	50	Unbiased-50k	1714.5	1745.3	30.836
13	50	Unbiased-50k	1714.5	1714.5	0
14	50	Unbiased-50k	1714.5	1720.6	6.0798
16	50	Unbiased-50k	1656	1684.7	28.75
17	60	Biased-50k	1656	1690.6	34.62
18	60	Biased-50k	1580.5	1606.6	26.167
19	60	Biased-50k	1684.7	1714.5	29.766
20	60	Biased-50k	1777.3	1777.3	0
21	60	Biased-50k	1575.3	1601.3	25.996
24	100	Unbiased-100k	1684.7	1714.5	29.766
25	100	Unbiased-100k	1684.7	1684.7	0
26	100	Unbiased-100k	1575.3	1628.2	52.864
27	100	Unbiased-100k	1580.5	1580.5	0
28	100	Unbiased-100k	1656	1714.5	58.515
29	110	Biased-100k	1684.7	1684.7	0
30	110	Biased-100k	1714.5	1777.3	62.802
31	110	Biased-100k	1745.3	1745.3	0
32	110	Biased-100k	1580.5	1777.3	196.84
34	110	Biased-100k	1810.5	1745.3	-65.125

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1575.3	1622.2	1684.7	56.343	1550.2	1615.1	1714.5	87.452	-26.167	-7.1887	29.766	32.007
50	1575.3	1675	1714.5	61.187	1606.6	1694.4	1745.3	53.573	0	19.393	31.298	15.113
60	1575.3	1654.8	1777.3	83.283	1601.3	1678.1	1777.3	74.705	0	23.31	34.62	13.494
100	1575.3	1636.3	1684.7	54.574	1580.5	1664.5	1714.5	58.713	0	28.229	58.515	27.93
110	1580.5	1707.1	1810.5	84.759	1684.7	1746	1777.3	37.796	-65.125	38.903	196.84	99.2

Device Test: 38.6 EA_GM(EA|Transconductance/VSNS2/3/3///90.9/634//0///@EA_GM)





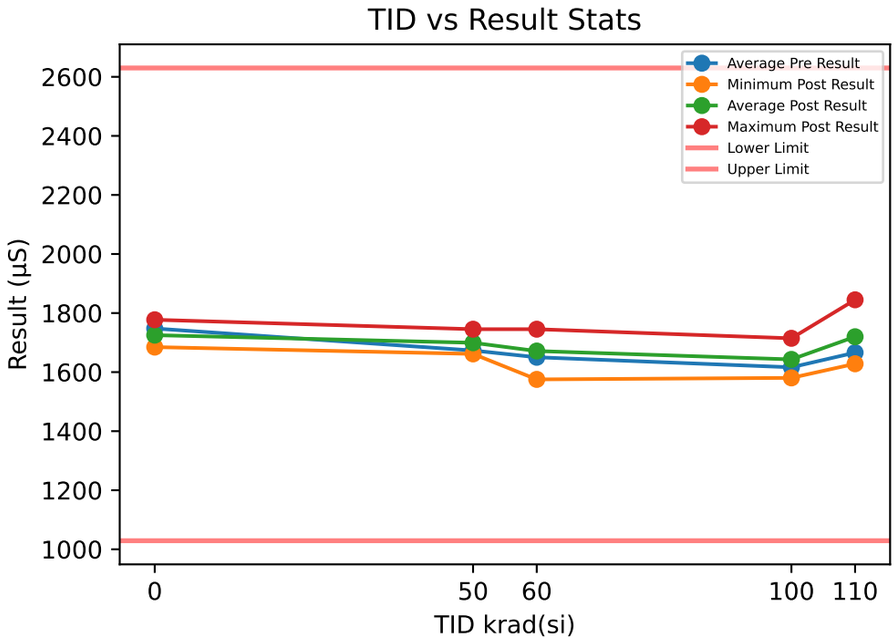
Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

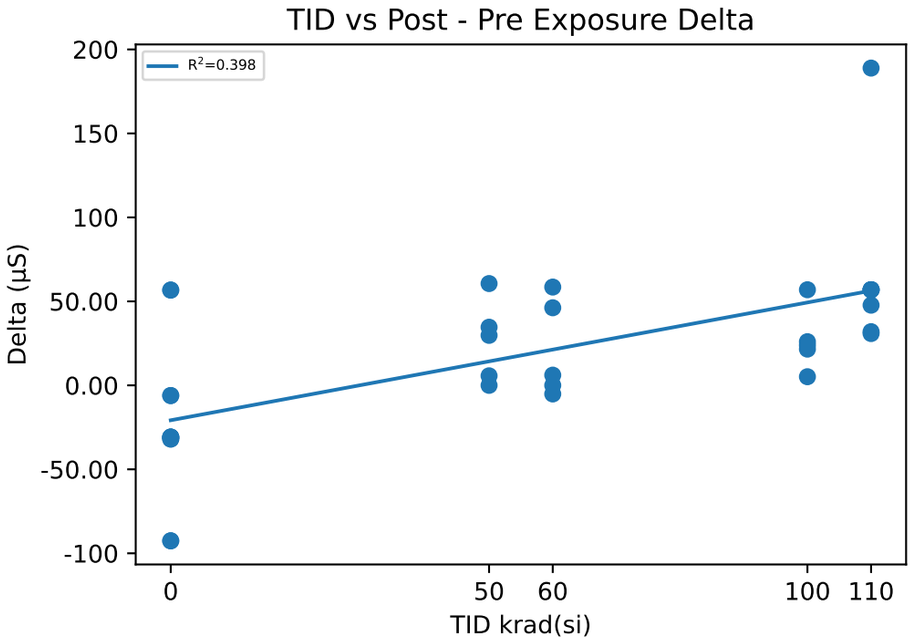
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1690.6	1720.6	29.975
2	0	CU2	1555.1	1555.1	0
3	0	CU3	1684.7	1684.7	0
11	50	Unbiased-50k	1575.3	1580.5	5.1314
12	50	Unbiased-50k	1601.3	1580.5	-20.864
13	50	Unbiased-50k	1684.7	1714.5	29.766
14	50	Unbiased-50k	1628.2	1656	27.785
16	50	Unbiased-50k	1628.2	1656	27.785
17	60	Biased-50k	1714.5	1745.3	30.836
18	60	Biased-50k	1555.1	1555.1	0
19	60	Biased-50k	1684.7	1720.6	35.845
20	60	Biased-50k	1714.5	1745.3	30.836
21	60	Biased-50k	1656	1684.7	28.75
24	100	Unbiased-100k	1628.2	1633.7	5.4821
25	100	Unbiased-100k	1628.2	1656	27.785
26	100	Unbiased-100k	1628.2	1633.7	5.4821
27	100	Unbiased-100k	1555.1	1580.5	25.328
28	100	Unbiased-100k	1628.2	1656	27.785
29	110	Biased-100k	1745.3	1745.3	0
30	110	Biased-100k	1684.7	1720.6	35.845
31	110	Biased-100k	1684.7	1745.3	60.602
32	110	Biased-100k	1684.7	1777.3	92.568
34	110	Biased-100k	1661.7	1720.6	58.924

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1555.1	1643.5	1690.6	76.573	1555.1	1653.5	1720.6	87.035	0	9.9918	29.975	17.306
50	1575.3	1623.6	1684.7	40.636	1580.5	1637.5	1714.5	57.267	-20.864	13.921	29.766	21.925
60	1555.1	1665	1714.5	66.032	1555.1	1690.2	1745.3	79.489	0	25.254	35.845	14.357
100	1555.1	1613.6	1628.2	32.674	1580.5	1632	1656	30.87	5.4821	18.372	27.785	11.81
110	1661.7	1692.2	1745.3	31.319	1720.6	1741.8	1777.3	23.377	0	49.588	92.568	34.291

Device Test: 38.7 EA_GM(EA|Transconductance/VSNS3/3/3///90.9/634//0///@EA_GM)





Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

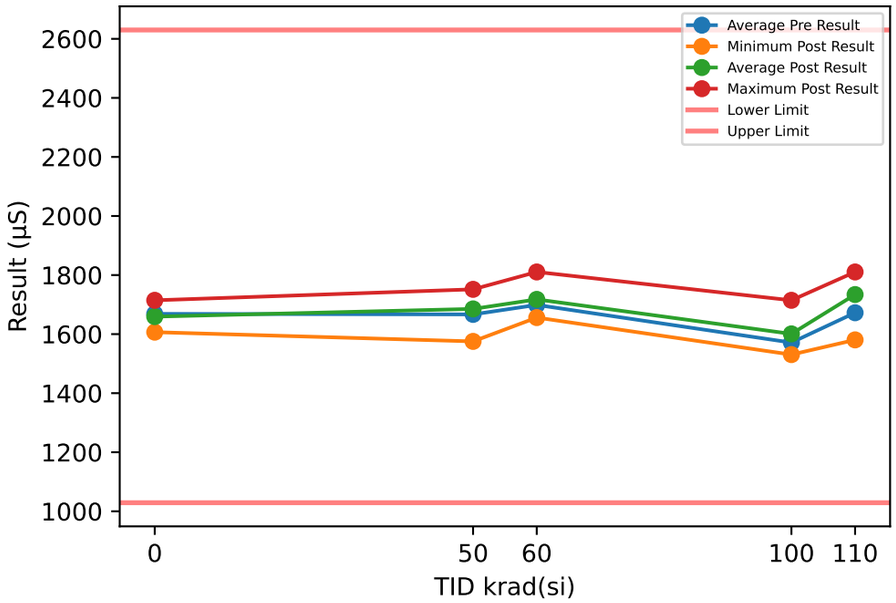
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1777.3	1745.3	-31.966
2	0	CU2	1720.6	1714.5	-6.0798
3	0	CU3	1745.3	1714.5	-30.836
11	50	Unbiased-50k	1656	1690.6	34.62
12	50	Unbiased-50k	1656	1661.7	5.6712
13	50	Unbiased-50k	1684.7	1684.7	0
14	50	Unbiased-50k	1684.7	1714.5	29.766
16	50	Unbiased-50k	1684.7	1745.3	60.602
17	60	Biased-50k	1745.3	1745.3	0
18	60	Biased-50k	1555.1	1601.3	46.192
19	60	Biased-50k	1714.5	1720.6	6.0798
20	60	Biased-50k	1656	1714.5	58.515
21	60	Biased-50k	1580.5	1575.3	-5.1314
24	100	Unbiased-100k	1575.3	1580.5	5.1314
25	100	Unbiased-100k	1690.6	1714.5	23.895
26	100	Unbiased-100k	1606.6	1628.2	21.566
27	100	Unbiased-100k	1575.3	1601.3	25.996
28	100	Unbiased-100k	1633.7	1690.6	56.923
29	110	Biased-100k	1714.5	1745.3	30.836
30	110	Biased-100k	1745.3	1777.3	31.966
31	110	Biased-100k	1580.5	1628.2	47.732
32	110	Biased-100k	1656	1844.9	188.9
34	110	Biased-100k	1633.7	1690.6	56.923

Test Statistics (µS)

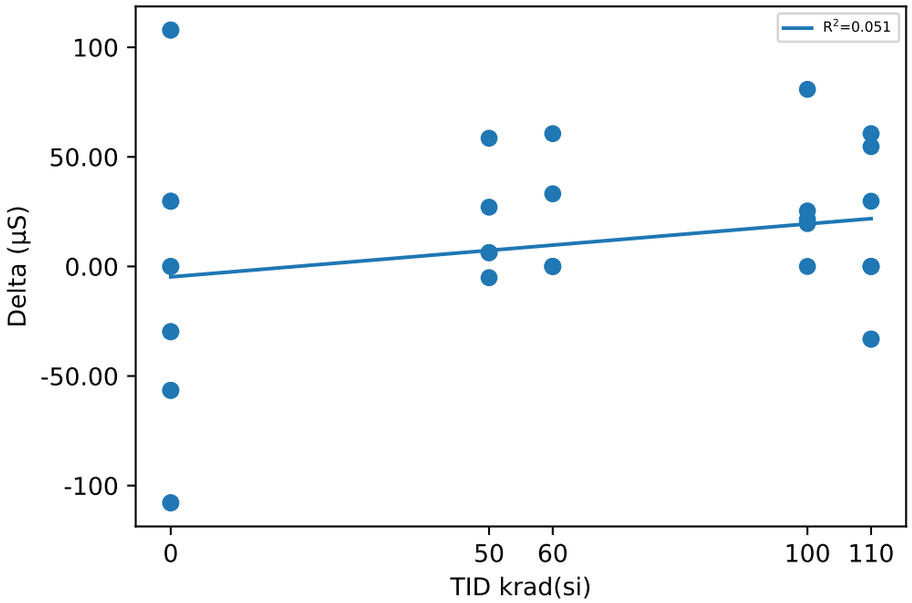
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1720.6	1747.7	1777.3	28.438	1714.5	1724.8	1745.3	17.803	-31.966	-22.961	-6.0798	14.63
50	1656	1673.2	1684.7	15.747	1661.7	1699.4	1745.3	31.84	0	26.132	60.602	24.367
60	1555.1	1650.3	1745.3	82.338	1575.3	1671.4	1745.3	77.267	-5.1314	21.131	58.515	29.105
100	1575.3	1616.3	1690.6	48.148	1580.5	1643	1714.5	57.542	5.1314	26.702	56.923	18.797
110	1580.5	1666	1745.3	65.397	1628.2	1737.3	1844.9	82.646	30.836	71.271	188.9	66.662

Device Test: 38.8 EA_GM(EA|Transconductance/VSNS4/3/3///90.9/634//0///@EA_GM)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



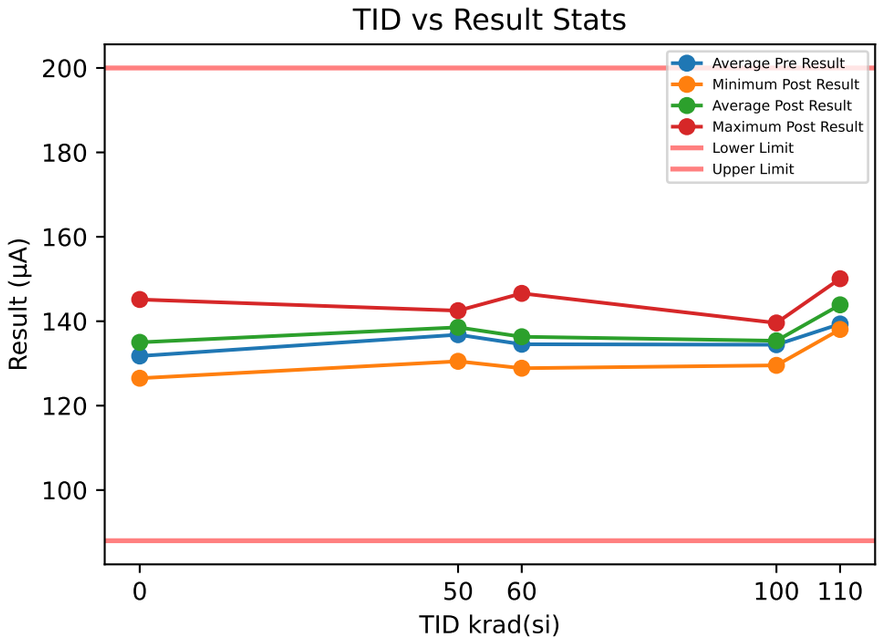
Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

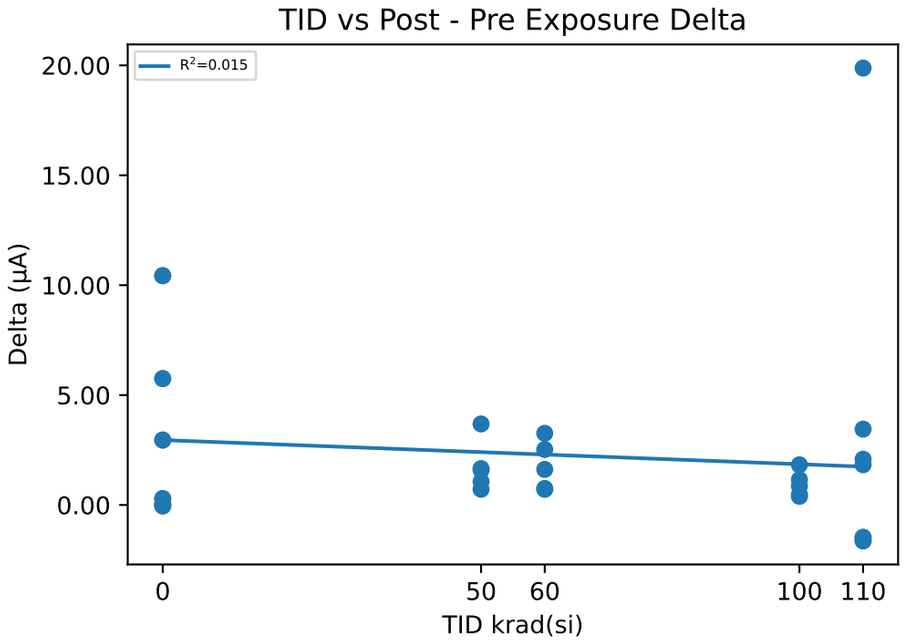
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1684.7	1714.5	29.766
2	0	CU2	1606.6	1606.6	0
3	0	CU3	1714.5	1684.7	-29.766
11	50	Unbiased-50k	1606.6	1633.7	27.048
12	50	Unbiased-50k	1656	1714.5	58.515
13	50	Unbiased-50k	1580.5	1575.3	-5.1314
14	50	Unbiased-50k	1745.3	1751.6	6.3009
16	50	Unbiased-50k	1745.3	1751.6	6.3009
17	60	Biased-50k	1714.5	1714.5	0
18	60	Biased-50k	1777.3	1810.5	33.159
19	60	Biased-50k	1661.7	1661.7	0
20	60	Biased-50k	1684.7	1745.3	60.602
21	60	Biased-50k	1656	1656	0
24	100	Unbiased-100k	1606.6	1628.2	21.566
25	100	Unbiased-100k	1530.6	1550.2	19.561
26	100	Unbiased-100k	1530.6	1530.6	0
27	100	Unbiased-100k	1555.1	1580.5	25.328
28	100	Unbiased-100k	1633.7	1714.5	80.818
29	110	Biased-100k	1525.8	1580.5	54.67
30	110	Biased-100k	1684.7	1745.3	60.602
31	110	Biased-100k	1656	1656	0
32	110	Biased-100k	1684.7	1714.5	29.766
34	110	Biased-100k	1810.5	1810.5	0

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1606.6	1668.6	1714.5	55.709	1606.6	1668.6	1714.5	55.709	-29.766	0	29.766	29.766
50	1580.5	1666.8	1745.3	76.691	1575.3	1685.4	1751.6	78.119	-5.1314	18.607	58.515	25.151
60	1656	1698.8	1777.3	49.548	1656	1717.6	1810.5	63.891	0	18.752	60.602	27.449
100	1530.6	1571.3	1633.7	46.67	1530.6	1600.8	1714.5	73.454	0	29.455	80.818	30.344
110	1525.8	1672.3	1810.5	101.4	1580.5	1701.4	1810.5	87.584	0	29.008	60.602	28.897

Device Test: 38.9 EA_SOURCE(EA|SourceCurrent/COMP1/3/3///90.9/634//0///@EA_SOURCE)





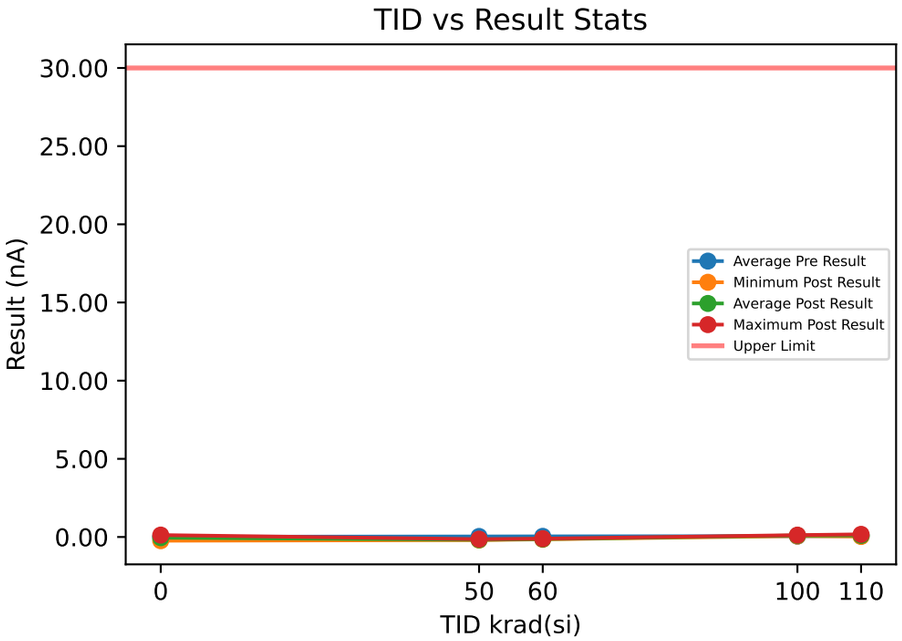
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

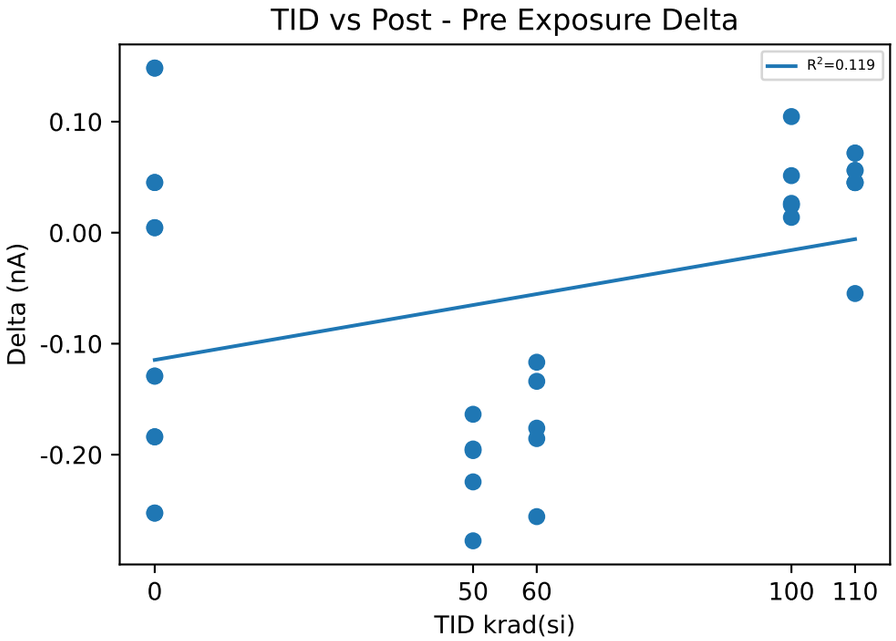
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	139.4	139.69	0.2909
2	0	CU2	129.35	129.39	0.0467
3	0	CU3	126.54	126.5	-0.0419
11	50	Unbiased-50k	129.79	130.5	0.7128
12	50	Unbiased-50k	141.28	142.35	1.0717
13	50	Unbiased-50k	138.82	142.51	3.6858
14	50	Unbiased-50k	139.03	140.62	1.5923
16	50	Unbiased-50k	135.12	136.77	1.6552
17	60	Biased-50k	136.31	137.02	0.7106
18	60	Biased-50k	127.25	128.87	1.6193
19	60	Biased-50k	137.95	138.7	0.7511
20	60	Biased-50k	143.34	146.6	3.2604
21	60	Biased-50k	127.9	130.42	2.5252
24	100	Unbiased-100k	139.11	139.59	0.4771
25	100	Unbiased-100k	136.98	138.14	1.1539
26	100	Unbiased-100k	128.72	130.54	1.8271
27	100	Unbiased-100k	129.15	129.55	0.3918
28	100	Unbiased-100k	138.19	139.05	0.8533
29	110	Biased-100k	136.22	138.05	1.8322
30	110	Biased-100k	143.81	147.26	3.4499
31	110	Biased-100k	142.07	144.16	2.0824
32	110	Biased-100k	130.19	150.07	19.877
34	110	Biased-100k	144.44	142.96	-1.474

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.54	131.76	139.4	6.7608	126.5	131.86	139.69	6.9329	-0.0419	0.098567	0.2909	0.17236
50	129.79	136.81	141.28	4.5018	130.5	138.55	142.51	5.0565	0.7128	1.7436	3.6858	1.1529
60	127.25	134.55	143.34	6.8805	128.87	136.32	146.6	7.107	0.7106	1.7733	3.2604	1.1152
100	128.72	134.43	139.11	5.0764	129.55	135.37	139.59	4.9038	0.3918	0.94064	1.8271	0.58203
110	130.19	139.35	144.44	6.058	138.05	144.5	150.07	4.5472	-1.474	5.1535	19.877	8.4272

Device Test: 39.1 IVSNS_LKG(EA|Leakage/VSNS1/7/7///90.9/634//0///@IVSNS_LKG)





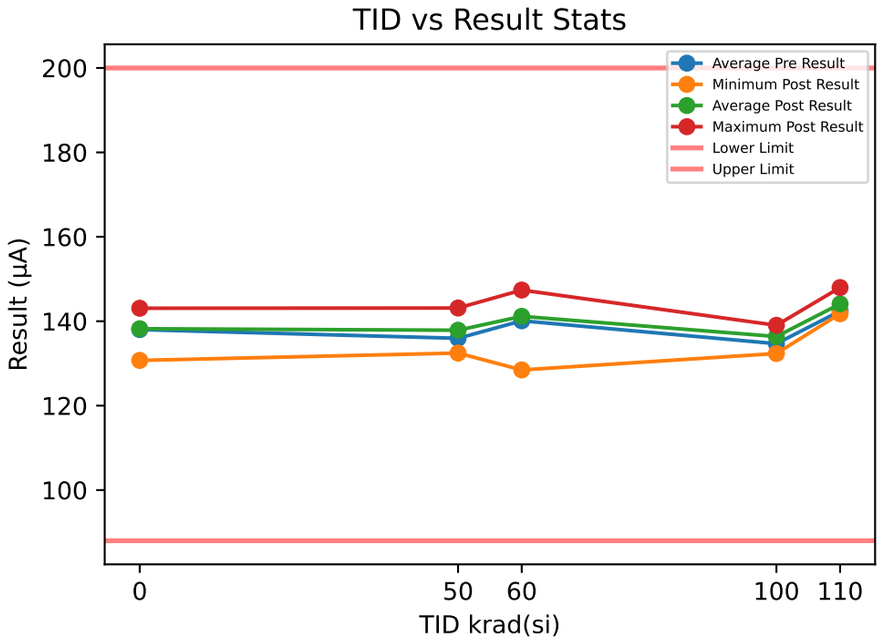
Test Results (Upper Limit = 30.0 (nA))

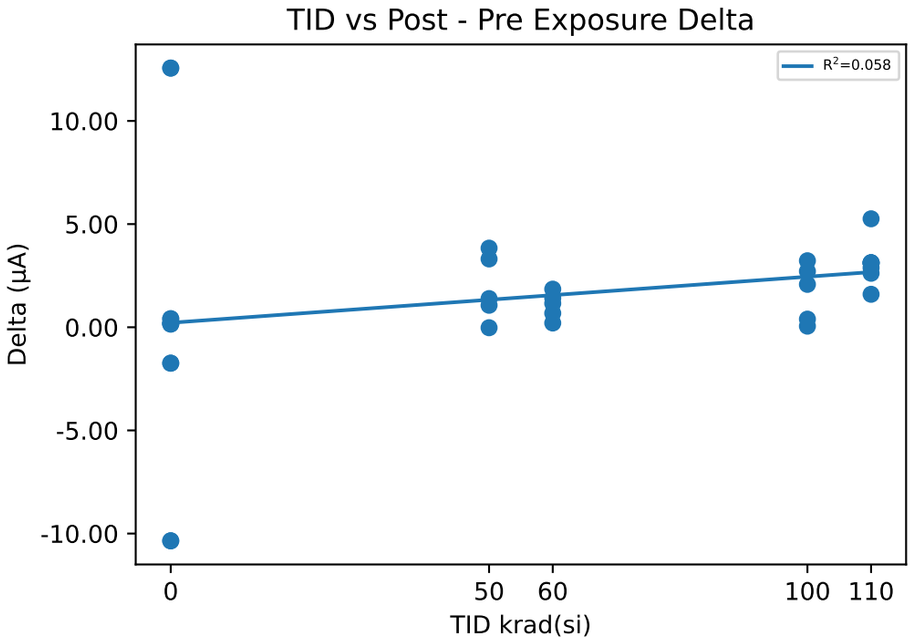
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.0146	-0.238	-0.2526
2	0	CU2	-0.0245	-0.1537	-0.1292
3	0	CU3	0.0568	-0.1271	-0.1839
11	50	Unbiased-50k	0.0568	-0.1381	-0.1949
12	50	Unbiased-50k	0.0161	-0.1802	-0.1963
13	50	Unbiased-50k	-0.0354	-0.199	-0.1636
14	50	Unbiased-50k	0.0552	-0.1693	-0.2245
16	50	Unbiased-50k	0.0818	-0.1958	-0.2776
17	60	Biased-50k	0.0365	-0.1396	-0.1761
18	60	Biased-50k	0.1099	-0.1459	-0.2558
19	60	Biased-50k	0.0177	-0.1162	-0.1339
20	60	Biased-50k	0.0787	-0.1068	-0.1855
21	60	Biased-50k	-0.0323	-0.149	-0.1167
24	100	Unbiased-100k	0.088	0.1144	0.0264
25	100	Unbiased-100k	0.0677	0.0925	0.0248
26	100	Unbiased-100k	0.0474	0.0988	0.0514
27	100	Unbiased-100k	-0.0417	0.0629	0.1046
28	100	Unbiased-100k	0.1068	0.1206	0.0138
29	110	Biased-100k	0.0255	0.0707	0.0452
30	110	Biased-100k	0.088	0.0332	-0.0548
31	110	Biased-100k	0.0333	0.0894	0.0561
32	110	Biased-100k	0.1146	0.1706	0.056
34	110	Biased-100k	0.0521	0.1238	0.0717

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0245	0.015633	0.0568	0.04066	-0.238	-0.17293	-0.1271	0.057898	-0.2526	-0.18857	-0.1292	0.061832
50	-0.0354	0.0349	0.0818	0.04579	-0.199	-0.17648	-0.1381	0.024591	-0.2776	-0.21138	-0.1636	0.042834
60	-0.0323	0.0421	0.1099	0.054997	-0.149	-0.1315	-0.1068	0.018864	-0.2558	-0.1736	-0.1167	0.054126
100	-0.0417	0.05364	0.1068	0.057734	0.0629	0.09784	0.1206	0.022597	0.0138	0.0442	0.1046	0.03646
110	0.0255	0.0627	0.1146	0.03773	0.0332	0.09754	0.1706	0.05233	-0.0548	0.03484	0.0717	0.050993

Device Test: 39.10 EA_SOURCE(EA|SourceCurrent/COMP2/7/7///90.9/634//0///@EA_SOURCE)





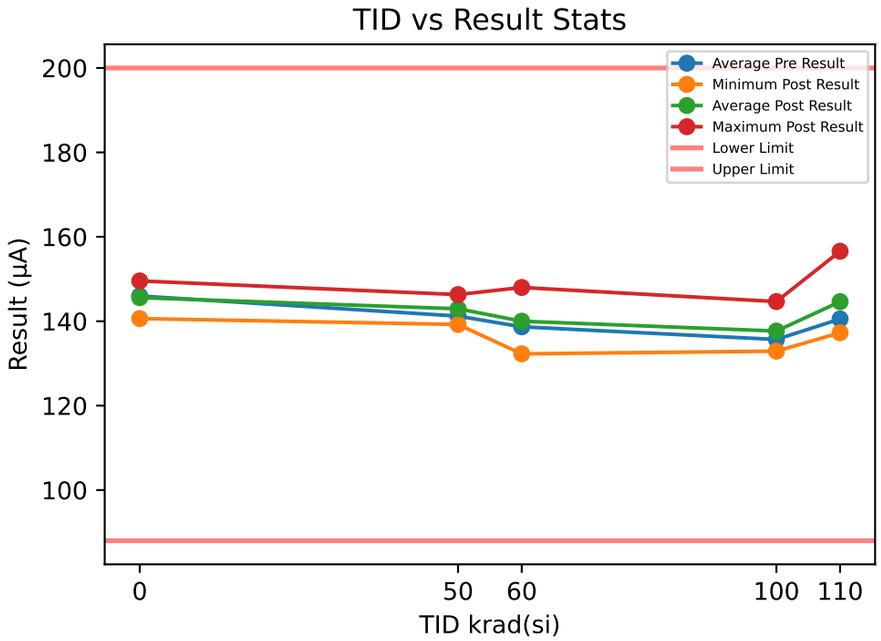
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

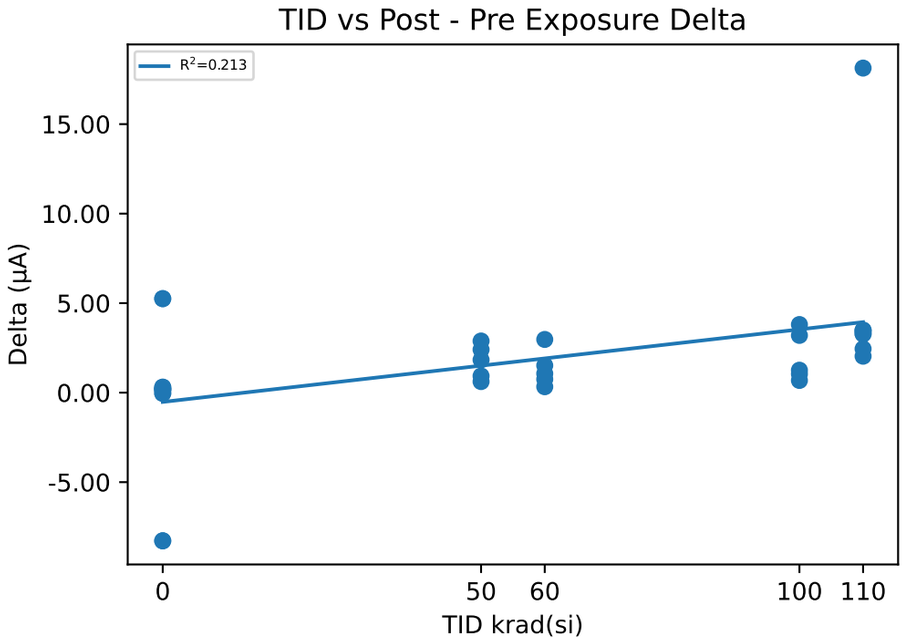
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	142.45	142.86	0.4122
2	0	CU2	130.51	130.72	0.207
3	0	CU3	141.09	141.24	0.1551
11	50	Unbiased-50k	131.41	132.8	1.39
12	50	Unbiased-50k	132.48	132.46	-0.0227
13	50	Unbiased-50k	139.82	143.13	3.3103
14	50	Unbiased-50k	136.82	140.66	3.8352
16	50	Unbiased-50k	139.24	140.31	1.0663
17	60	Biased-50k	145.47	147.32	1.8476
18	60	Biased-50k	127.78	128.45	0.6791
19	60	Biased-50k	141.12	142.54	1.4183
20	60	Biased-50k	147.18	147.39	0.2053
21	60	Biased-50k	138.96	140.12	1.1558
24	100	Unbiased-100k	136.52	136.57	0.0531
25	100	Unbiased-100k	135.81	139.03	3.2237
26	100	Unbiased-100k	136.78	137.17	0.3946
27	100	Unbiased-100k	129.64	132.36	2.7148
28	100	Unbiased-100k	134.65	136.73	2.079
29	110	Biased-100k	145.27	146.87	1.5981
30	110	Biased-100k	142.37	144.99	2.6171
31	110	Biased-100k	143.05	145.93	2.8834
32	110	Biased-100k	142.72	147.98	5.2572
34	110	Biased-100k	138.65	141.77	3.1241

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	130.51	138.02	142.45	6.534	130.72	138.27	142.86	6.5925	0.1551	0.2581	0.4122	0.13595
50	131.41	135.95	139.82	3.8504	132.46	137.87	143.13	4.9109	-0.0227	1.9158	3.8352	1.6113
60	127.78	140.1	147.18	7.6363	128.45	141.16	147.39	7.7645	0.2053	1.0612	1.8476	0.63903
100	129.64	134.68	136.78	2.9352	132.36	136.37	139.03	2.4508	0.0531	1.693	3.2237	1.4063
110	138.65	142.41	145.27	2.3897	141.77	145.51	147.98	2.3642	1.5981	3.096	5.2572	1.3407

Device Test: 39.11 EA_SOURCE(EA|SourceCurrent/COMP3/7/7///90.9/634//0///@EA_SOURCE)





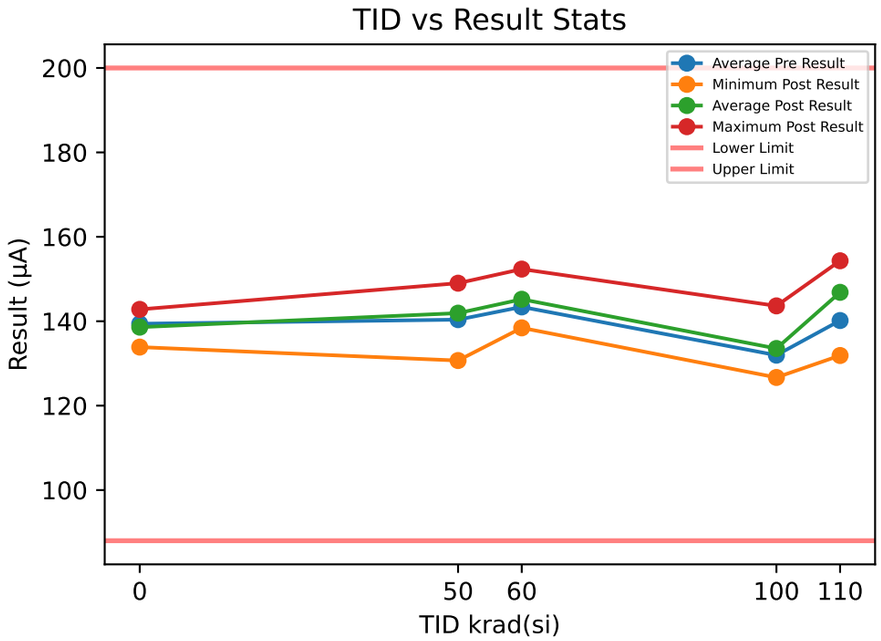
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

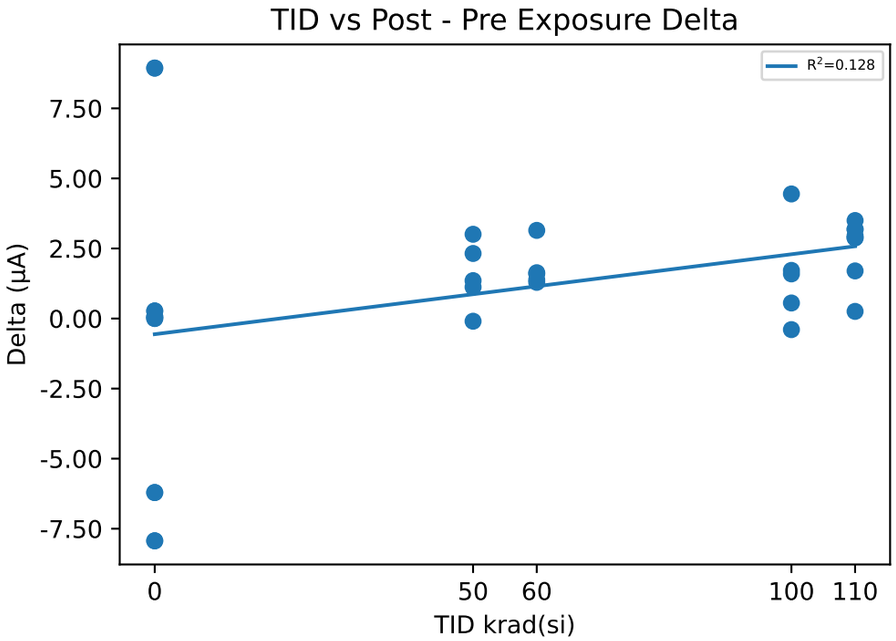
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	148.91	149.21	0.3046
2	0	CU2	144.3	144.5	0.1979
3	0	CU3	144.75	144.9	0.1521
11	50	Unbiased-50k	139.48	142.36	2.8848
12	50	Unbiased-50k	137.4	139.23	1.8324
13	50	Unbiased-50k	141.69	142.31	0.6183
14	50	Unbiased-50k	143.61	144.54	0.9319
16	50	Unbiased-50k	143.91	146.31	2.4054
17	60	Biased-50k	146.94	148	1.0655
18	60	Biased-50k	131.01	132.53	1.5172
19	60	Biased-50k	144.12	144.87	0.7489
20	60	Biased-50k	139.39	142.36	2.9718
21	60	Biased-50k	131.94	132.27	0.3305
24	100	Unbiased-100k	131.87	132.91	1.0435
25	100	Unbiased-100k	143.98	144.66	0.6817
26	100	Unbiased-100k	133.45	137.25	3.8046
27	100	Unbiased-100k	132.44	133.69	1.2545
28	100	Unbiased-100k	136.66	139.86	3.199
29	110	Biased-100k	142.34	145.77	3.424
30	110	Biased-100k	148.82	150.85	2.0359
31	110	Biased-100k	134.82	137.27	2.4463
32	110	Biased-100k	138.44	156.58	18.131
34	110	Biased-100k	138.26	141.75	3.489

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	144.3	145.99	148.91	2.5398	144.5	146.2	149.21	2.6125	0.1521	0.2182	0.3046	0.07825
50	137.4	141.22	143.91	2.7734	139.23	142.95	146.31	2.6647	0.6183	1.7346	2.8848	0.95825
60	131.01	138.68	146.94	7.1147	132.27	140.01	148	7.2258	0.3305	1.3268	2.9718	1.017
100	131.87	135.68	143.98	4.996	132.91	137.67	144.66	4.8033	0.6817	1.9967	3.8046	1.4056
110	134.82	140.54	148.82	5.3395	137.27	146.44	156.58	7.563	2.0359	5.9052	18.131	6.8629

Device Test: 39.12 EA_SOURCE(EA|SourceCurrent/COMP4/7/7///90.9/634//0///@EA_SOURCE)





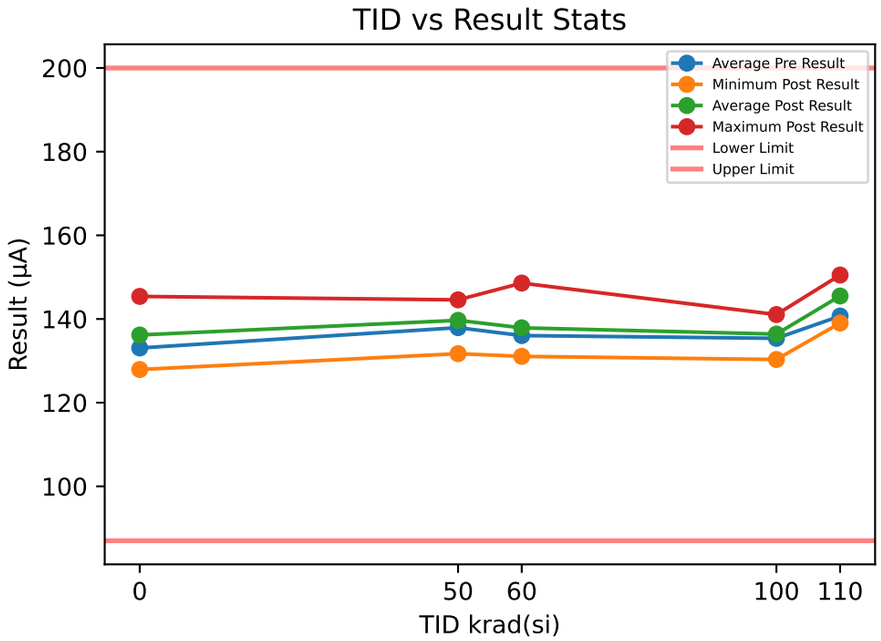
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

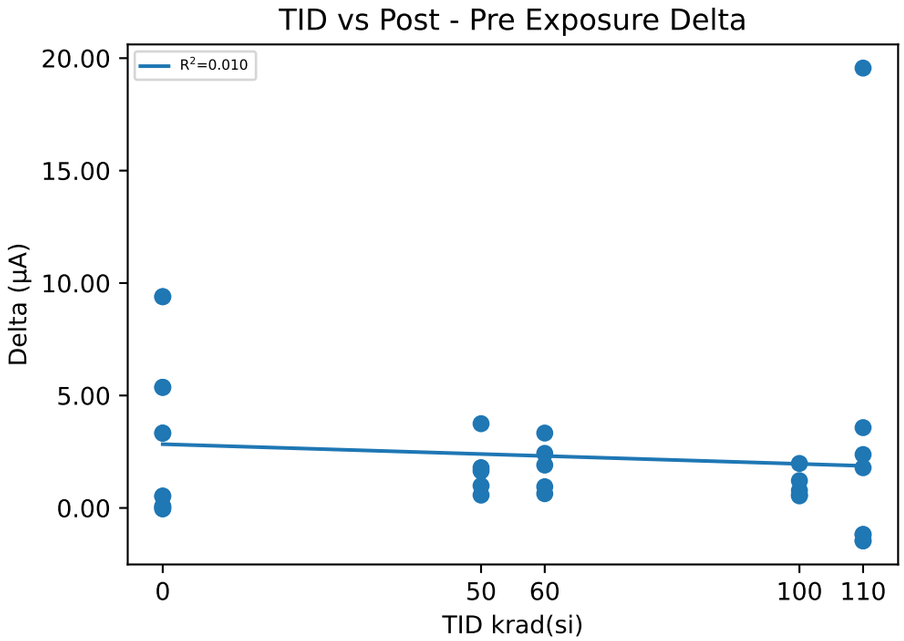
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	142.42	142.69	0.2701
2	0	CU2	133.87	133.87	0.0019
3	0	CU3	141.93	142	0.0677
11	50	Unbiased-50k	134.99	137.31	2.3215
12	50	Unbiased-50k	141.07	144.08	3.0073
13	50	Unbiased-50k	130.78	130.69	-0.0963
14	50	Unbiased-50k	147.66	149.01	1.3528
16	50	Unbiased-50k	147.37	148.49	1.1232
17	60	Biased-50k	145.55	147.15	1.5978
18	60	Biased-50k	150.97	152.35	1.3815
19	60	Biased-50k	138.86	140.49	1.6347
20	60	Biased-50k	144.46	147.6	3.1457
21	60	Biased-50k	137.14	138.43	1.2914
24	100	Unbiased-100k	135.52	137.12	1.5931
25	100	Unbiased-100k	129.27	128.87	-0.3957
26	100	Unbiased-100k	126.12	126.68	0.5545
27	100	Unbiased-100k	129.68	131.4	1.7178
28	100	Unbiased-100k	139.19	143.64	4.4455
29	110	Biased-100k	128.38	131.88	3.4974
30	110	Biased-100k	142.03	143.73	1.6992
31	110	Biased-100k	138.44	138.69	0.2547
32	110	Biased-100k	140.84	143.79	2.9529
34	110	Biased-100k	151.14	154.32	3.1846

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	133.87	139.41	142.42	4.8019	133.87	139.52	142.69	4.9043	0.0019	0.11323	0.2701	0.13978
50	130.78	140.37	147.66	7.4741	130.69	141.91	149.01	7.835	-0.0963	1.5417	3.0073	1.1885
60	137.14	143.39	150.97	5.5421	138.43	145.2	152.35	5.6718	1.2914	1.8102	3.1457	0.76033
100	126.12	131.96	139.19	5.2795	126.68	133.54	143.64	6.8592	-0.3957	1.583	4.4455	1.8156
110	128.38	140.17	151.14	8.1576	131.88	142.48	154.32	8.2199	0.2547	2.3178	3.4974	1.3403

Device Test: 39.13 EA_SINK(EA|SinkCurrent/COMP1/7/7///90.9/634//0///@EA_SINK)





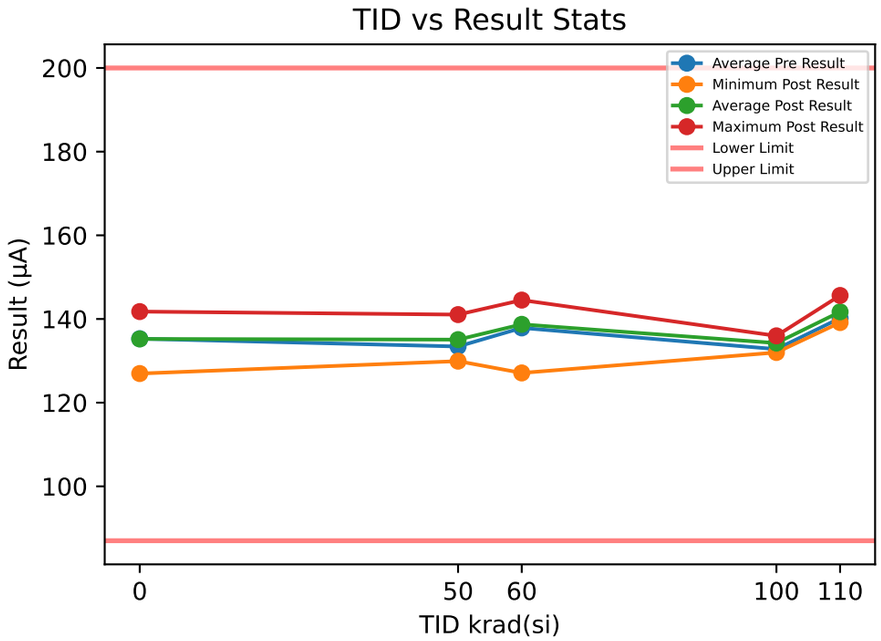
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

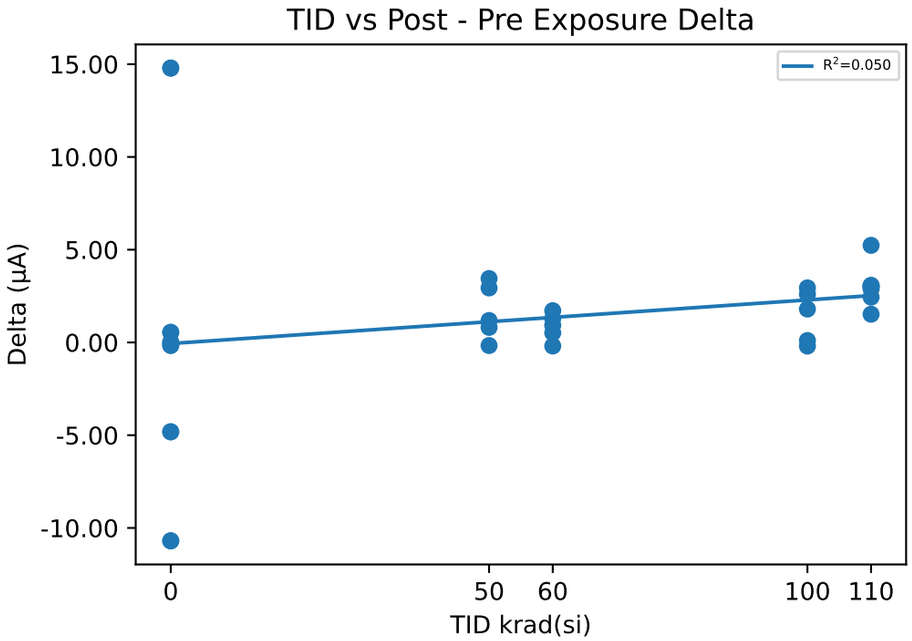
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	140.04	140.56	0.5249
2	0	CU2	131.21	131.28	0.0703
3	0	CU3	127.96	127.92	-0.0366
11	50	Unbiased-50k	131.13	131.71	0.5708
12	50	Unbiased-50k	141.49	142.48	0.9871
13	50	Unbiased-50k	140.83	144.58	3.7464
14	50	Unbiased-50k	139.8	141.45	1.6436
16	50	Unbiased-50k	136.39	138.18	1.7924
17	60	Biased-50k	138.15	138.78	0.6341
18	60	Biased-50k	129.58	131.49	1.9057
19	60	Biased-50k	138.57	139.52	0.9445
20	60	Biased-50k	145.25	148.58	3.3294
21	60	Biased-50k	128.64	131.06	2.4256
24	100	Unbiased-100k	140.48	141.06	0.5745
25	100	Unbiased-100k	137.69	138.91	1.2123
26	100	Unbiased-100k	130.04	132.02	1.9783
27	100	Unbiased-100k	129.78	130.32	0.5376
28	100	Unbiased-100k	138.88	139.66	0.7782
29	110	Biased-100k	137.25	139.04	1.7889
30	110	Biased-100k	145.28	148.85	3.5718
31	110	Biased-100k	143.89	146.26	2.3738
32	110	Biased-100k	130.95	150.51	19.559
34	110	Biased-100k	146.15	144.96	-1.1814

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	127.96	133.07	140.04	6.2492	127.92	133.25	140.56	6.5464	-0.0366	0.1862	0.5249	0.29815
50	131.13	137.93	141.49	4.2766	131.71	139.68	144.58	5.0191	0.5708	1.7481	3.7464	1.2218
60	128.64	136.04	145.25	6.9331	131.06	137.89	148.58	7.1658	0.6341	1.8479	3.3294	1.0979
100	129.78	135.38	140.48	5.0856	130.32	136.39	141.06	4.8663	0.5376	1.0162	1.9783	0.60102
110	130.95	140.7	146.15	6.4783	139.04	145.92	150.51	4.417	-1.1814	5.2225	19.559	8.2034

Device Test: 39.14 EA_SINK(EA|SinkCurrent/COMP2/7/7///90.9/634//0///@EA_SINK)





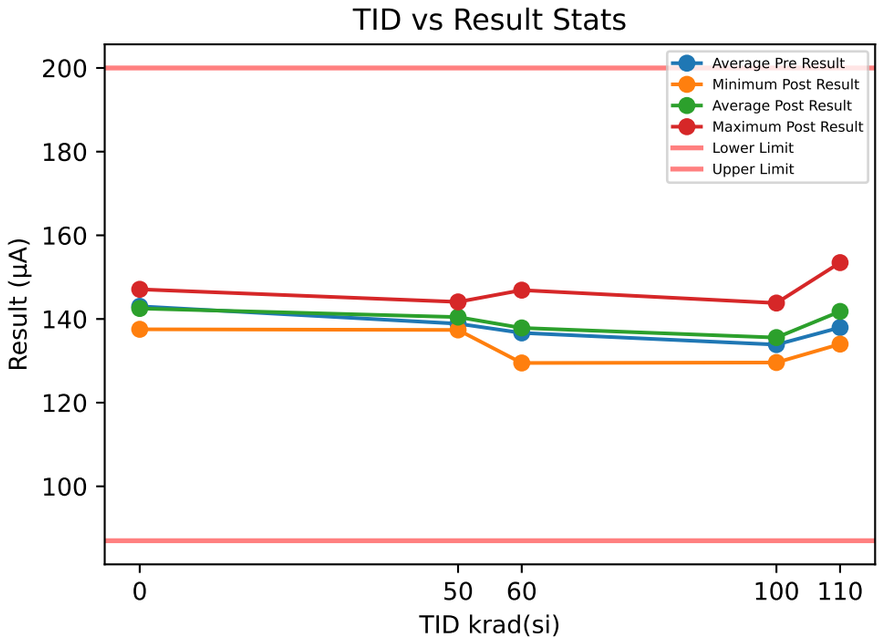
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

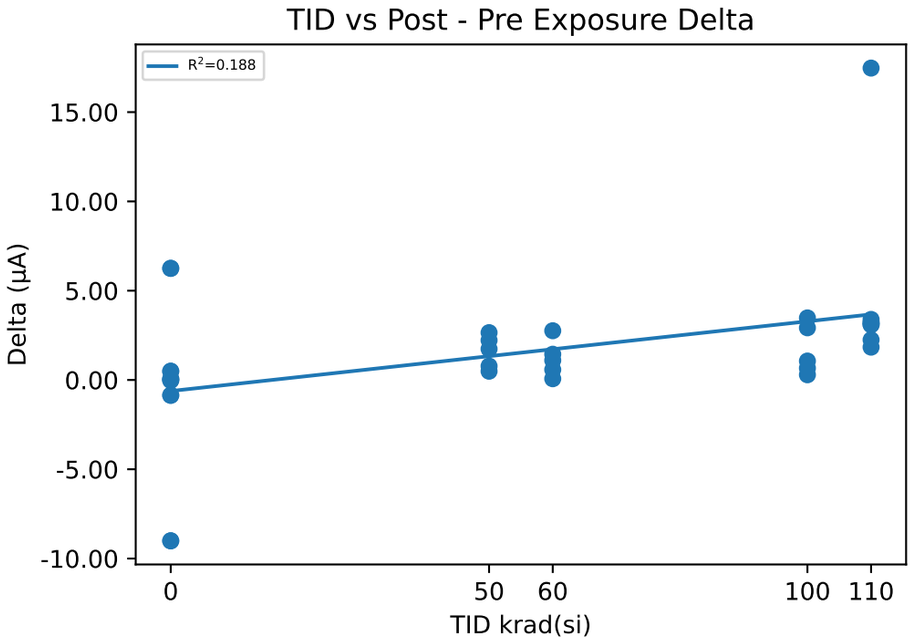
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	141.22	141.76	0.543
2	0	CU2	126.98	126.99	0.0132
3	0	CU3	137.66	137.5	-0.1571
11	50	Unbiased-50k	129.21	130.4	1.1825
12	50	Unbiased-50k	130.09	129.92	-0.1671
13	50	Unbiased-50k	138.11	141.05	2.9388
14	50	Unbiased-50k	133.97	137.42	3.4436
16	50	Unbiased-50k	135.74	136.55	0.8128
17	60	Biased-50k	142.76	144.47	1.7108
18	60	Biased-50k	126.58	127.1	0.5193
19	60	Biased-50k	138.54	139.83	1.2901
20	60	Biased-50k	144.71	144.52	-0.1925
21	60	Biased-50k	136.76	137.68	0.9222
24	100	Unbiased-100k	134.01	133.81	-0.1948
25	100	Unbiased-100k	133.03	135.97	2.943
26	100	Unbiased-100k	134.94	135.05	0.1025
27	100	Unbiased-100k	129.4	131.99	2.5943
28	100	Unbiased-100k	132.6	134.4	1.8005
29	110	Biased-100k	143.24	144.76	1.5212
30	110	Biased-100k	140.09	142.53	2.4443
31	110	Biased-100k	141.12	144	2.8828
32	110	Biased-100k	140.39	145.62	5.2345
34	110	Biased-100k	136.16	139.23	3.0709

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.98	135.28	141.22	7.409	126.99	135.42	141.76	7.6004	-0.1571	0.13303	0.543	0.36511
50	129.21	133.43	138.11	3.7575	129.92	135.07	141.05	4.7906	-0.1671	1.6421	3.4436	1.5082
60	126.58	137.87	144.71	7.0668	127.1	138.72	144.52	7.1406	-0.1925	0.84998	1.7108	0.73076
100	129.4	132.8	134.94	2.1049	131.99	134.24	135.97	1.492	-0.1948	1.4491	2.943	1.4302
110	136.16	140.2	143.24	2.5718	139.23	143.23	145.62	2.5073	1.5212	3.0307	5.2345	1.3696

Device Test: 39.15 EA_SINK(EA|SinkCurrent/COMP3/7/7///90.9/634//0///@EA_SINK)





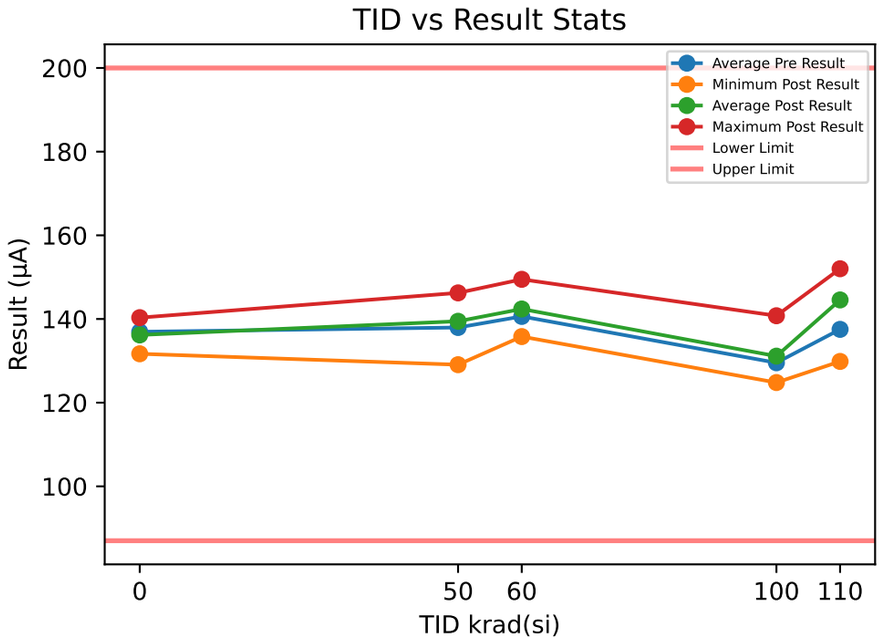
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

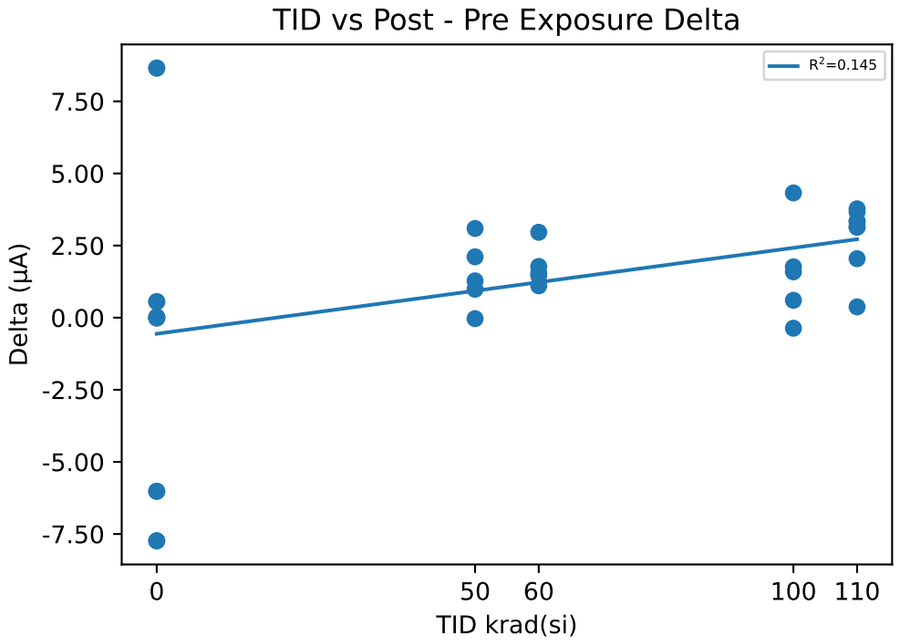
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	146.54	147.03	0.4897
2	0	CU2	140.84	140.91	0.0651
3	0	CU3	141.7	141.68	-0.0197
11	50	Unbiased-50k	137.01	139.66	2.6512
12	50	Unbiased-50k	135.64	137.38	1.7381
13	50	Unbiased-50k	138.96	139.45	0.4898
14	50	Unbiased-50k	140.92	141.69	0.7778
16	50	Unbiased-50k	141.86	144.08	2.2225
17	60	Biased-50k	145.79	146.89	1.099
18	60	Biased-50k	129.67	131.11	1.4418
19	60	Biased-50k	140.92	141.5	0.5784
20	60	Biased-50k	137.55	140.31	2.7575
21	60	Biased-50k	129.42	129.49	0.0696
24	100	Unbiased-100k	128.93	129.59	0.662
25	100	Unbiased-100k	143.52	143.81	0.2914
26	100	Unbiased-100k	131.67	135.15	3.4762
27	100	Unbiased-100k	130.15	131.21	1.0611
28	100	Unbiased-100k	135.1	138.02	2.9217
29	110	Biased-100k	140.32	143.71	3.3906
30	110	Biased-100k	146.05	147.89	1.8382
31	110	Biased-100k	131.75	134	2.2476
32	110	Biased-100k	136.01	153.47	17.466
34	110	Biased-100k	135.69	138.9	3.2129

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	140.84	143.03	146.54	3.0739	140.91	143.21	147.03	3.3359	-0.0197	0.17837	0.4897	0.27294
50	135.64	138.88	141.86	2.5988	137.38	140.45	144.08	2.5396	0.4898	1.5759	2.6512	0.92429
60	129.42	136.67	145.79	7.1359	129.49	137.86	146.89	7.3563	0.0696	1.1893	2.7575	1.0196
100	128.93	133.87	143.52	5.8667	129.59	135.56	143.81	5.6747	0.2914	1.6825	3.4762	1.4244
110	131.75	137.96	146.05	5.4434	134	143.59	153.47	7.5849	1.8382	5.6312	17.466	6.6479

Device Test: 39.16 EA_SINK(EA|SinkCurrent/COMP4/7/7///90.9/634//0///@EA_SINK)





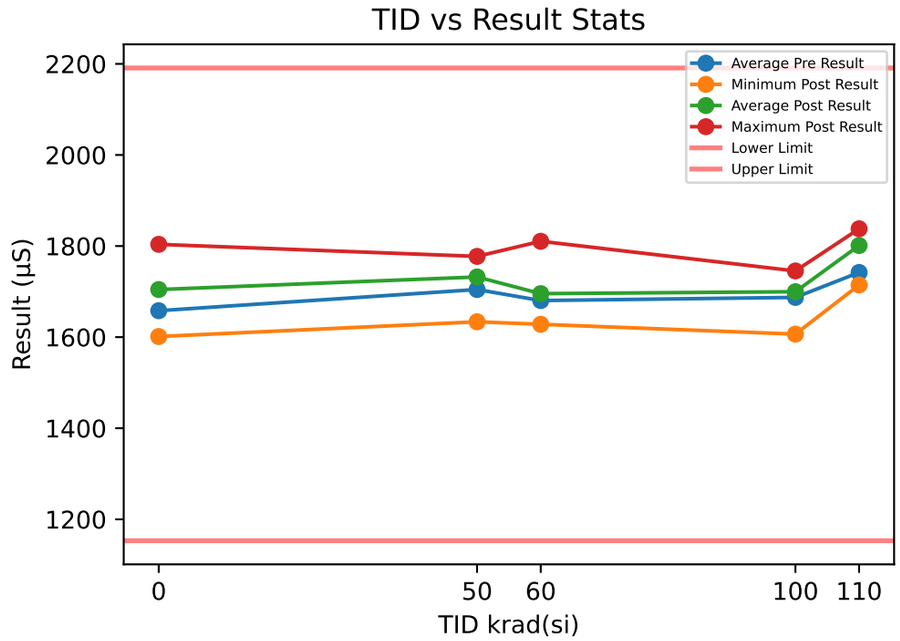
Test Results (Lower Limit = 87.0, Upper Limit = 200.0 (µA))

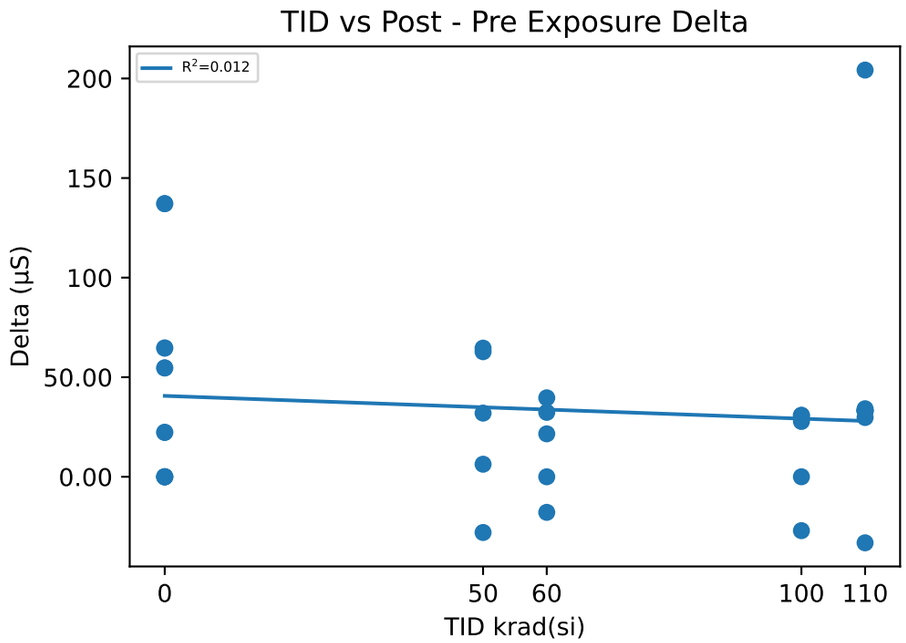
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	139.74	140.3	0.5548
2	0	CU2	131.67	131.69	0.0209
3	0	CU3	139.42	139.41	-0.0104
11	50	Unbiased-50k	132.89	135	2.1098
12	50	Unbiased-50k	138.65	141.75	3.0925
13	50	Unbiased-50k	129.11	129.08	-0.0334
14	50	Unbiased-50k	144.96	146.24	1.2771
16	50	Unbiased-50k	144.22	145.21	0.9851
17	60	Biased-50k	142.84	144.4	1.5577
18	60	Biased-50k	148.02	149.48	1.4563
19	60	Biased-50k	135.66	137.44	1.7751
20	60	Biased-50k	141.86	144.82	2.9609
21	60	Biased-50k	134.69	135.8	1.1049
24	100	Unbiased-100k	132.78	134.36	1.5894
25	100	Unbiased-100k	126.2	125.83	-0.3658
26	100	Unbiased-100k	124.2	124.81	0.6021
27	100	Unbiased-100k	128.05	129.81	1.7625
28	100	Unbiased-100k	136.45	140.78	4.3251
29	110	Biased-100k	126.19	129.85	3.6641
30	110	Biased-100k	139.86	141.9	2.0454
31	110	Biased-100k	135.48	135.86	0.3738
32	110	Biased-100k	137.41	141.18	3.7746
34	110	Biased-100k	148.67	152.01	3.3435

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	131.67	136.94	139.74	4.5727	131.69	137.13	140.3	4.7359	-0.0104	0.18843	0.5548	0.31767
50	129.11	137.97	144.96	6.9422	129.08	139.45	146.24	7.2791	-0.0334	1.4862	3.0925	1.1804
60	134.69	140.62	148.02	5.5016	135.8	142.39	149.48	5.6629	1.1049	1.771	2.9609	0.70783
100	124.2	129.54	136.45	5.0015	124.81	131.12	140.78	6.5814	-0.3658	1.5827	4.3251	1.7544
110	126.19	137.52	148.67	8.0966	129.85	140.16	152.01	8.2039	0.3738	2.6403	3.7746	1.4422

Device Test: 39.17 EA_GM_25C(EA|Transconductance/VSNS1/7/7///90.9/634//0///@EA_GM_25C)





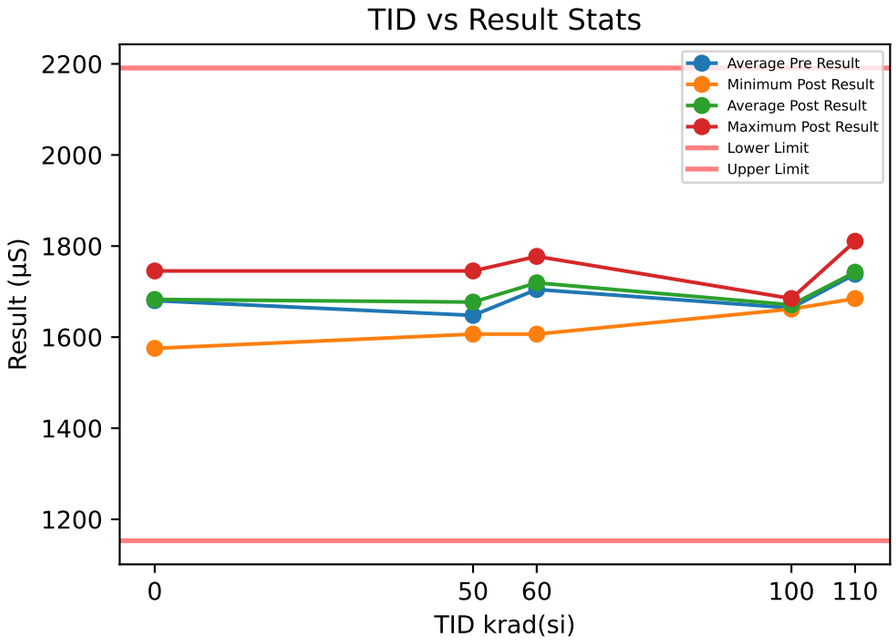
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

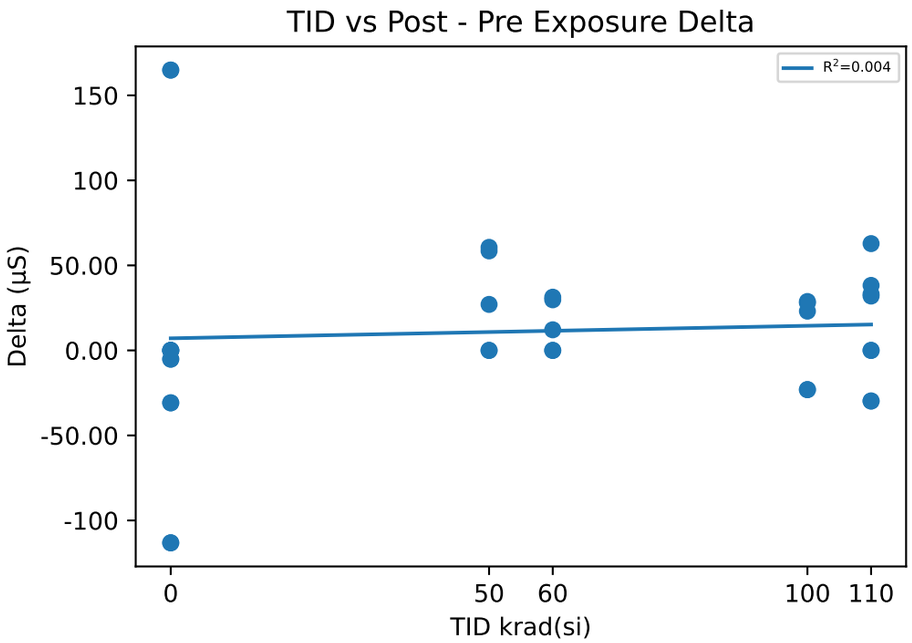
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1739.1	1739.1	0
2	0	CU2	1633.7	1656	22.303
3	0	CU3	1601.3	1601.3	0
11	50	Unbiased-50k	1661.7	1633.7	-27.974
12	50	Unbiased-50k	1745.3	1777.3	31.966
13	50	Unbiased-50k	1714.5	1777.3	62.802
14	50	Unbiased-50k	1745.3	1751.6	6.3009
16	50	Unbiased-50k	1656	1720.6	64.595
17	60	Biased-50k	1708.5	1690.6	-17.858
18	60	Biased-50k	1606.6	1628.2	21.566
19	60	Biased-50k	1714.5	1714.5	0
20	60	Biased-50k	1770.8	1810.5	39.645
21	60	Biased-50k	1601.3	1633.7	32.35
24	100	Unbiased-100k	1745.3	1745.3	0
25	100	Unbiased-100k	1714.5	1745.3	30.836
26	100	Unbiased-100k	1628.2	1656	27.785
27	100	Unbiased-100k	1633.7	1606.6	-27.048
28	100	Unbiased-100k	1714.5	1745.3	30.836
29	110	Biased-100k	1684.7	1714.5	29.766
30	110	Biased-100k	1803.7	1837.9	34.162
31	110	Biased-100k	1810.5	1777.3	-33.159
32	110	Biased-100k	1633.7	1837.9	204.21
34	110	Biased-100k	1777.3	1810.5	33.159

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1601.3	1658	1739.1	72.031	1601.3	1665.5	1739.1	69.362	0	7.4343	22.303	12.877
50	1656	1704.6	1745.3	43.659	1633.7	1732.1	1777.3	59.764	-27.974	27.538	64.595	39.272
60	1601.3	1680.4	1770.8	73.856	1628.2	1695.5	1810.5	74.081	-17.858	15.141	39.645	23.749
100	1628.2	1687.2	1745.3	52.952	1606.6	1699.7	1745.3	64.847	-27.048	12.482	30.836	25.624
110	1633.7	1742	1810.5	78.67	1714.5	1795.6	1837.9	51.745	-33.159	53.628	204.21	88.846

Device Test: 39.18 EA_GM_25C(EA|Transconductance/VSNS2/7/7///90.9/634//0///@EA_GM_25C)





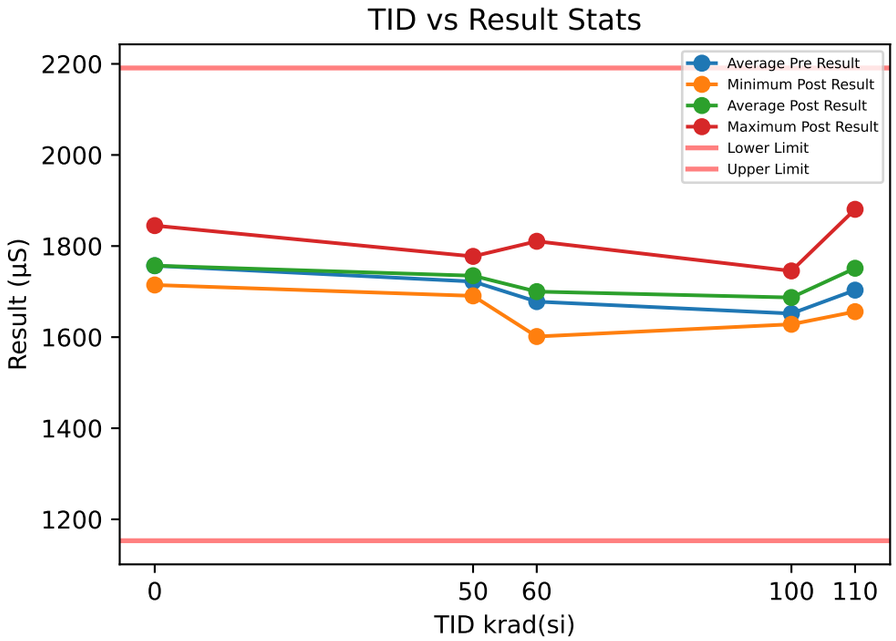
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

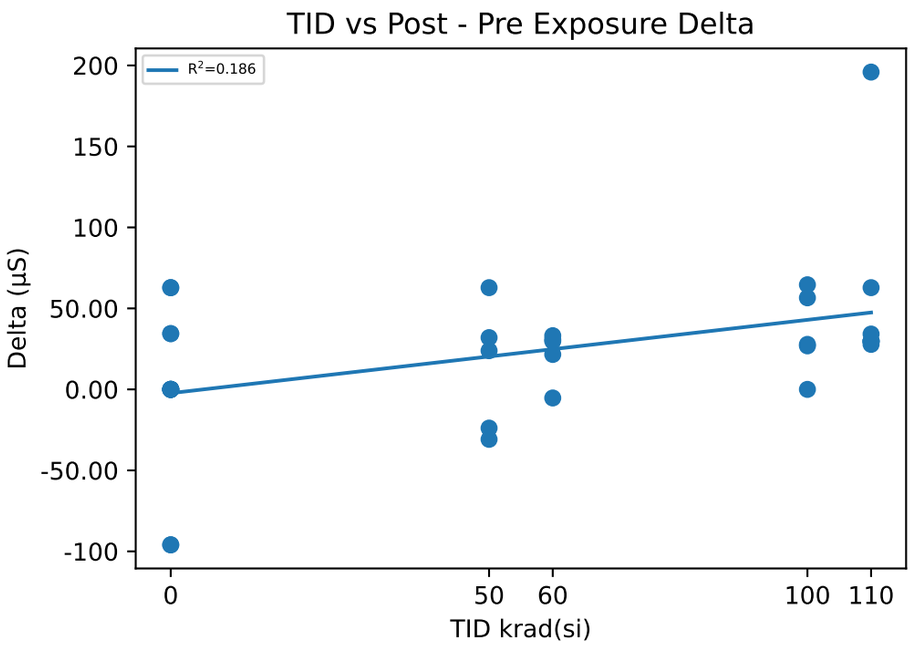
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1745.3	1745.3	0
2	0	CU2	1580.5	1575.3	-5.1314
3	0	CU3	1714.5	1714.5	0
11	50	Unbiased-50k	1606.6	1606.6	0
12	50	Unbiased-50k	1606.6	1633.7	27.048
13	50	Unbiased-50k	1684.7	1745.3	60.602
14	50	Unbiased-50k	1656	1714.5	58.515
16	50	Unbiased-50k	1684.7	1684.7	0
17	60	Biased-50k	1777.3	1777.3	0
18	60	Biased-50k	1575.3	1606.6	31.298
19	60	Biased-50k	1708.5	1720.6	12.117
20	60	Biased-50k	1777.3	1777.3	0
21	60	Biased-50k	1684.7	1714.5	29.766
24	100	Unbiased-100k	1684.7	1661.7	-23.079
25	100	Unbiased-100k	1661.7	1684.7	23.079
26	100	Unbiased-100k	1684.7	1661.7	-23.079
27	100	Unbiased-100k	1633.7	1661.7	27.974
28	100	Unbiased-100k	1656	1684.7	28.75
29	110	Biased-100k	1777.3	1810.5	33.159
30	110	Biased-100k	1739.1	1777.3	38.222
31	110	Biased-100k	1745.3	1777.3	31.966
32	110	Biased-100k	1714.5	1777.3	62.802
34	110	Biased-100k	1714.5	1714.5	0

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1580.5	1680.1	1745.3	87.652	1575.3	1678.4	1745.3	90.57	-5.1314	-1.7105	0	2.9626
50	1606.6	1647.7	1684.7	39.321	1606.6	1677	1745.3	56.929	0	29.233	60.602	29.814
60	1575.3	1704.6	1777.3	83.202	1606.6	1719.3	1777.3	69.726	0	14.636	31.298	15.34
100	1633.7	1664.2	1684.7	21.498	1661.7	1670.9	1684.7	12.641	-23.079	6.7291	28.75	27.297
110	1714.5	1738.1	1777.3	26	1714.5	1771.4	1810.5	34.885	0	33.23	62.802	22.39

Device Test: 39.19 EA_GM_25C(EA|Transconductance/VSNS3/7/7///90.9/634//0///@EA_GM_25C)





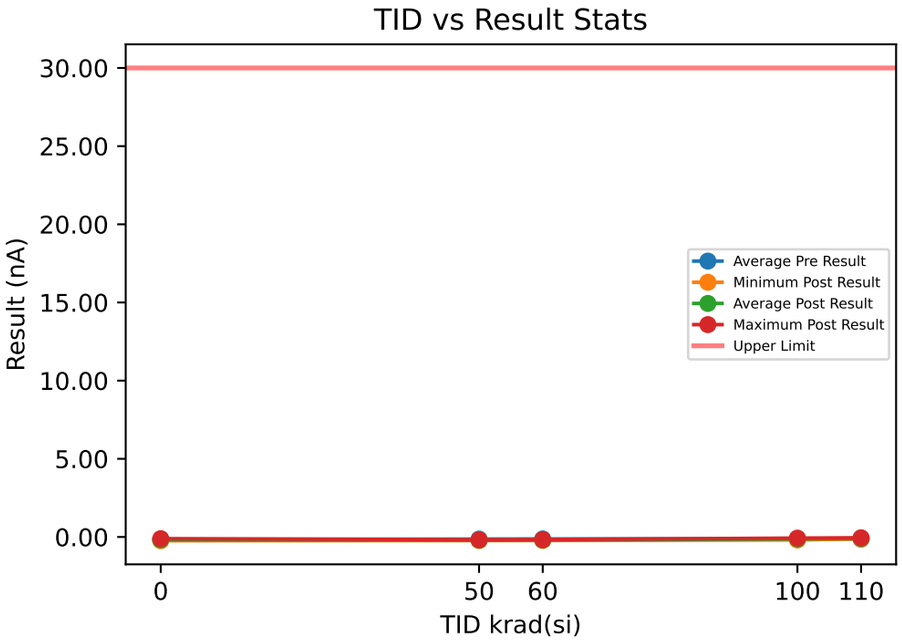
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

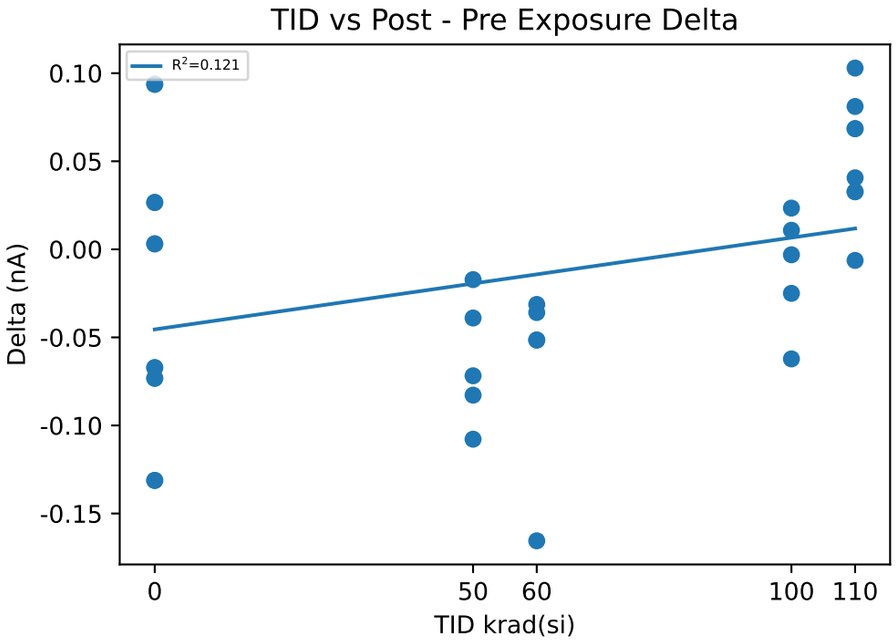
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1810.5	1844.9	34.419
2	0	CU2	1714.5	1714.5	0
3	0	CU3	1745.3	1745.3	0
11	50	Unbiased-50k	1690.6	1714.5	23.895
12	50	Unbiased-50k	1714.5	1690.6	-23.895
13	50	Unbiased-50k	1745.3	1714.5	-30.836
14	50	Unbiased-50k	1745.3	1777.3	31.966
16	50	Unbiased-50k	1714.5	1777.3	62.802
17	60	Biased-50k	1777.3	1810.5	33.159
18	60	Biased-50k	1606.6	1601.3	-5.3024
19	60	Biased-50k	1714.5	1745.3	30.836
20	60	Biased-50k	1684.7	1714.5	29.766
21	60	Biased-50k	1606.6	1628.2	21.566
24	100	Unbiased-100k	1601.3	1628.2	26.868
25	100	Unbiased-100k	1745.3	1745.3	0
26	100	Unbiased-100k	1628.2	1684.7	56.535
27	100	Unbiased-100k	1628.2	1656	27.785
28	100	Unbiased-100k	1656	1720.6	64.595
29	110	Biased-100k	1714.5	1777.3	62.802
30	110	Biased-100k	1803.7	1837.9	34.162
31	110	Biased-100k	1628.2	1656	27.785
32	110	Biased-100k	1684.7	1880.6	195.9
34	110	Biased-100k	1684.7	1714.5	29.766

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1714.5	1756.8	1810.5	48.991	1714.5	1768.2	1844.9	68.141	0	11.473	34.419	19.872
50	1690.6	1722.1	1745.3	23.384	1690.6	1734.8	1777.3	39.97	-30.836	12.786	62.802	39.501
60	1606.6	1678	1777.3	73.186	1601.3	1700	1810.5	85.671	-5.3024	22.005	33.159	15.879
100	1601.3	1651.8	1745.3	55.74	1628.2	1687	1745.3	47.316	0	35.157	64.595	25.897
110	1628.2	1703.2	1803.7	64.306	1656	1773.3	1880.6	90.732	27.785	70.083	195.9	71.742

Device Test: 39.2 IVSNS_LKG(EA|Leakage/VSNS2/7/7///90.9/634//0///@IVSNS_LKG)





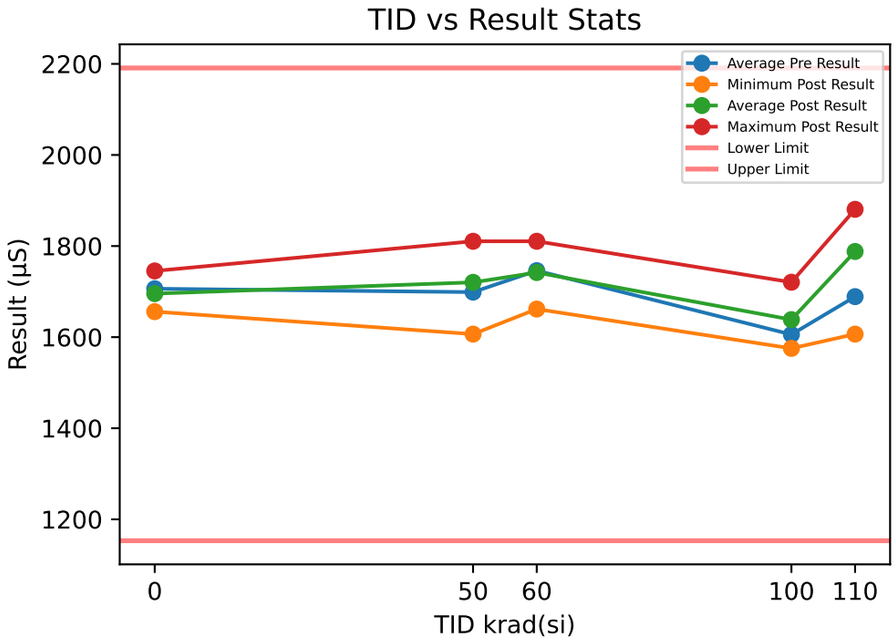
Test Results (Upper Limit = 30.0 (nA))

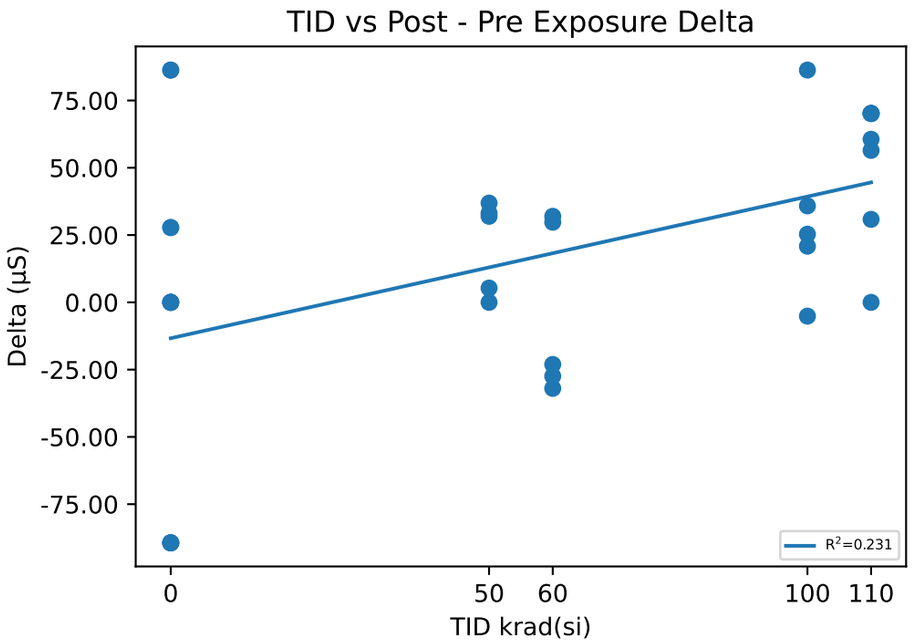
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.1069	-0.2381	-0.1312
2	0	CU2	-0.2022	-0.1991	0.0031
3	0	CU3	-0.1725	-0.2397	-0.0672
11	50	Unbiased-50k	-0.1241	-0.2319	-0.1078
12	50	Unbiased-50k	-0.1366	-0.2084	-0.0718
13	50	Unbiased-50k	-0.1585	-0.1757	-0.0172
14	50	Unbiased-50k	-0.1241	-0.2069	-0.0828
16	50	Unbiased-50k	-0.1413	-0.1803	-0.039
17	60	Biased-50k	-0.1522	-0.1881	-0.0359
18	60	Biased-50k	-0.1163	-0.1678	-0.0515
19	60	Biased-50k	-0.1506	-0.1819	-0.0313
20	60	Biased-50k	-0.0617	-0.2272	-0.1655
21	60	Biased-50k	-0.1585	-0.21	-0.0515
24	100	Unbiased-100k	-0.1335	-0.1101	0.0234
25	100	Unbiased-100k	-0.1288	-0.191	-0.0622
26	100	Unbiased-100k	-0.0851	-0.0743	0.0108
27	100	Unbiased-100k	-0.1225	-0.1256	-0.0031
28	100	Unbiased-100k	-0.1147	-0.1397	-0.025
29	110	Biased-100k	-0.1678	-0.0867	0.0811
30	110	Biased-100k	-0.0648	-0.0711	-0.0063
31	110	Biased-100k	-0.1569	-0.054	0.1029
32	110	Biased-100k	-0.1678	-0.1272	0.0406
34	110	Biased-100k	-0.1303	-0.0618	0.0685

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2022	-0.16053	-0.1069	0.048764	-0.2397	-0.22563	-0.1991	0.022992	-0.1312	-0.0651	0.0031	0.067175
50	-0.1585	-0.13692	-0.1241	0.014263	-0.2319	-0.20064	-0.1757	0.02298	-0.1078	-0.06372	-0.0172	0.035873
60	-0.1585	-0.12786	-0.0617	0.040494	-0.2272	-0.195	-0.1678	0.023563	-0.1655	-0.06714	-0.0313	0.055732
100	-0.1335	-0.11692	-0.0851	0.019135	-0.191	-0.12814	-0.0743	0.042766	-0.0622	-0.01122	0.0234	0.033683
110	-0.1678	-0.13752	-0.0648	0.043444	-0.1272	-0.08016	-0.054	0.028979	-0.0063	0.05736	0.1029	0.042116

Device Test: 39.20 EA_GM_25C(EA|Transconductance/VSNS4/7/7///90.9/634//0///@EA_GM_25C)





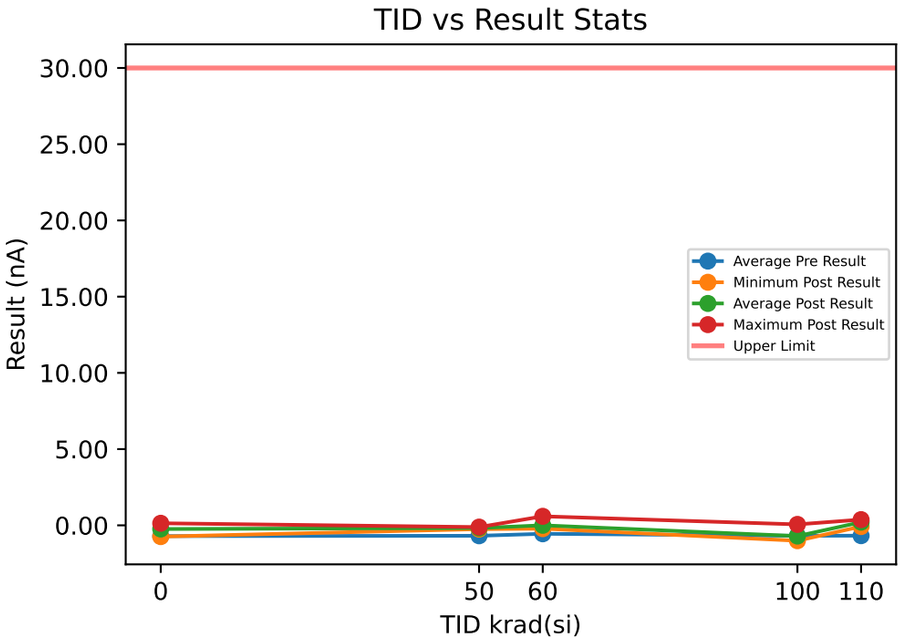
Test Results (Lower Limit = 1153.0, Upper Limit = 2191.0 (µS))

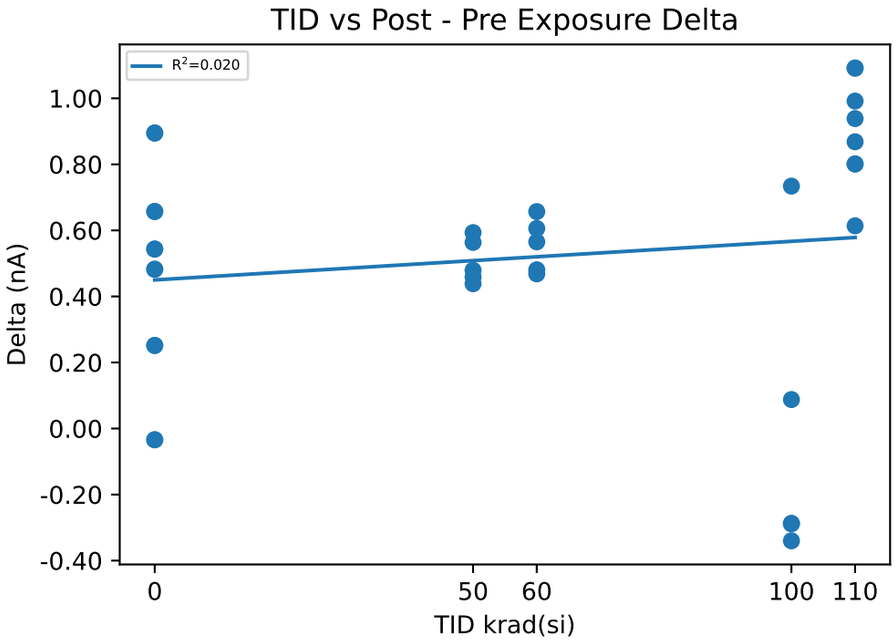
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1745.3	1745.3	0
2	0	CU2	1628.2	1656	27.785
3	0	CU3	1745.3	1745.3	0
11	50	Unbiased-50k	1661.7	1661.7	0
12	50	Unbiased-50k	1708.5	1745.3	36.873
13	50	Unbiased-50k	1601.3	1606.6	5.3024
14	50	Unbiased-50k	1777.3	1810.5	33.159
16	50	Unbiased-50k	1745.3	1777.3	31.966
17	60	Biased-50k	1777.3	1745.3	-31.966
18	60	Biased-50k	1837.9	1810.5	-27.431
19	60	Biased-50k	1684.7	1661.7	-23.079
20	60	Biased-50k	1745.3	1777.3	31.966
21	60	Biased-50k	1684.7	1714.5	29.766
24	100	Unbiased-100k	1628.2	1714.5	86.301
25	100	Unbiased-100k	1580.5	1575.3	-5.1314
26	100	Unbiased-100k	1555.1	1580.5	25.328
27	100	Unbiased-100k	1580.5	1601.3	20.864
28	100	Unbiased-100k	1684.7	1720.6	35.845
29	110	Biased-100k	1550.2	1606.6	56.463
30	110	Biased-100k	1714.5	1745.3	30.836
31	110	Biased-100k	1684.7	1684.7	0
32	110	Biased-100k	1684.7	1745.3	60.602
34	110	Biased-100k	1810.5	1880.6	70.173

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1628.2	1706.3	1745.3	67.629	1656	1715.6	1745.3	51.587	0	9.2617	27.785	16.042
50	1601.3	1698.8	1777.3	69.465	1606.6	1720.3	1810.5	84.208	0	21.46	36.873	17.367
60	1684.7	1746	1837.9	65.06	1661.7	1741.9	1810.5	57.349	-31.966	-4.1488	31.966	32.127
100	1555.1	1605.8	1684.7	51.435	1575.3	1638.4	1720.6	72.891	-5.1314	32.641	86.301	33.573
110	1550.2	1688.9	1810.5	93.157	1606.6	1732.5	1880.6	100.5	0	43.615	70.173	28.392

Device Test: 39.3 IVSNS_LKG(EA|Leakage/VSNS3/7/7///90.9/634//0///@IVSNS_LKG)





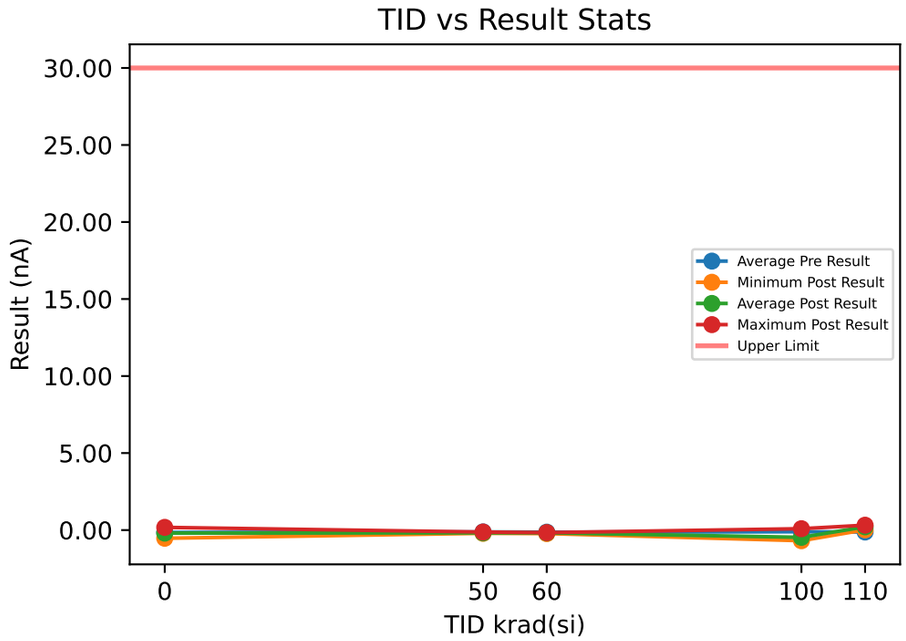
Test Results (Upper Limit = 30.0 (nA))

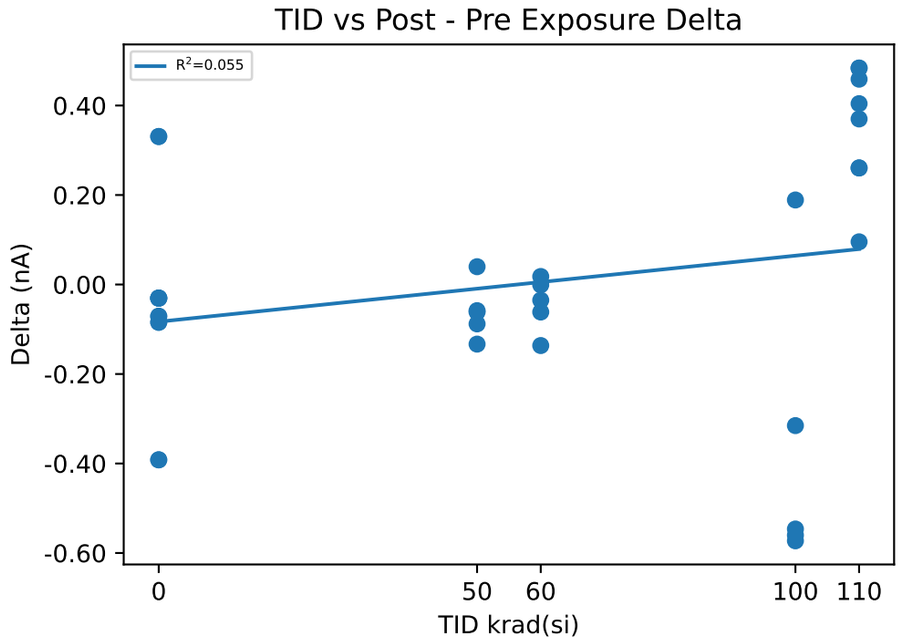
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.7053	-0.223	0.4823
2	0	CU2	-0.7599	-0.1026	0.6573
3	0	CU3	-0.6569	-0.1135	0.5434
11	50	Unbiased-50k	-0.6881	-0.2496	0.4385
12	50	Unbiased-50k	-0.6694	-0.2105	0.4589
13	50	Unbiased-50k	-0.6788	-0.1151	0.5637
14	50	Unbiased-50k	-0.6709	-0.1917	0.4792
16	50	Unbiased-50k	-0.7162	-0.1229	0.5933
17	60	Biased-50k	-0.699	-0.2183	0.4807
18	60	Biased-50k	-0.6866	-0.1213	0.5653
19	60	Biased-50k	-0.6959	-0.0901	0.6058
20	60	Biased-50k	-0.6257	-0.1573	0.4684
21	60	Biased-50k	-0.0652	0.5917	0.6569
24	100	Unbiased-100k	-0.685	-0.5973	0.0877
25	100	Unbiased-100k	-0.6959	-0.9845	-0.2886
26	100	Unbiased-100k	-0.6725	0.0616	0.7341
27	100	Unbiased-100k	-0.7037	-0.9908	-0.2871
28	100	Unbiased-100k	-0.6694	-1.0095	-0.3401
29	110	Biased-100k	-0.6944	-0.0805	0.6139
30	110	Biased-100k	-0.6366	0.302	0.9386
31	110	Biased-100k	-0.6631	0.3286	0.9917
32	110	Biased-100k	-0.6803	0.1881	0.8684
34	110	Biased-100k	-0.7162	0.3754	1.0916

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.7599	-0.70737	-0.6569	0.051531	-0.223	-0.14637	-0.1026	0.06659	0.4823	0.561	0.6573	0.088818
50	-0.7162	-0.68468	-0.6694	0.019126	-0.2496	-0.17796	-0.1151	0.057799	0.4385	0.50672	0.5933	0.067899
60	-0.699	-0.55448	-0.0652	0.27514	-0.2183	0.00094	0.5917	0.33367	0.4684	0.55542	0.6569	0.080761
100	-0.7037	-0.6853	-0.6694	0.014728	-1.0095	-0.7041	0.0616	0.46146	-0.3401	-0.0188	0.7341	0.45448
110	-0.7162	-0.67812	-0.6366	0.030288	-0.0805	0.22272	0.3754	0.18299	0.6139	0.90084	1.0916	0.1799

Device Test: 39.4 IVSNS_LKG(EA|Leakage/VSNS4/7/7///90.9/634//0///@IVSNS_LKG)





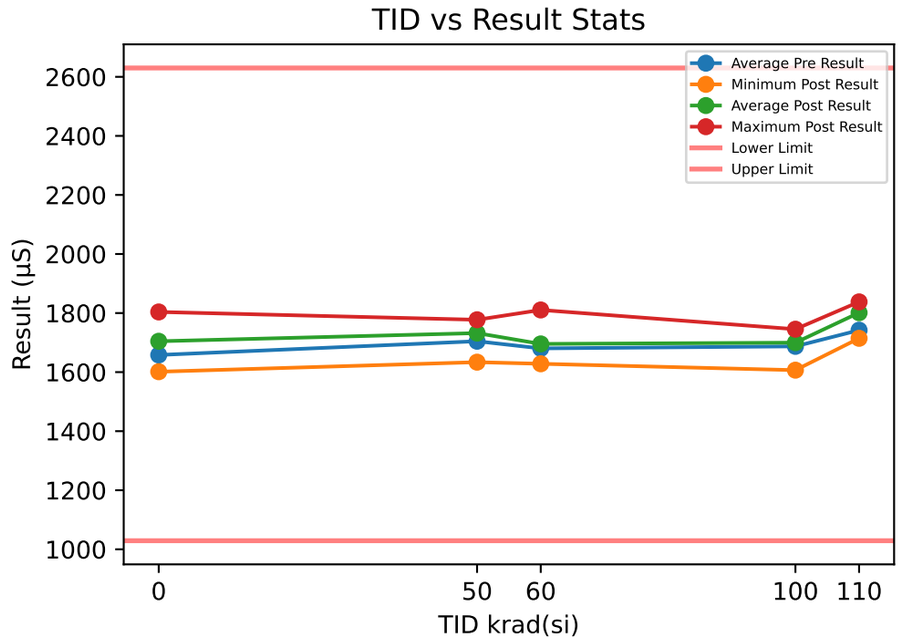
Test Results (Upper Limit = 30.0 (nA))

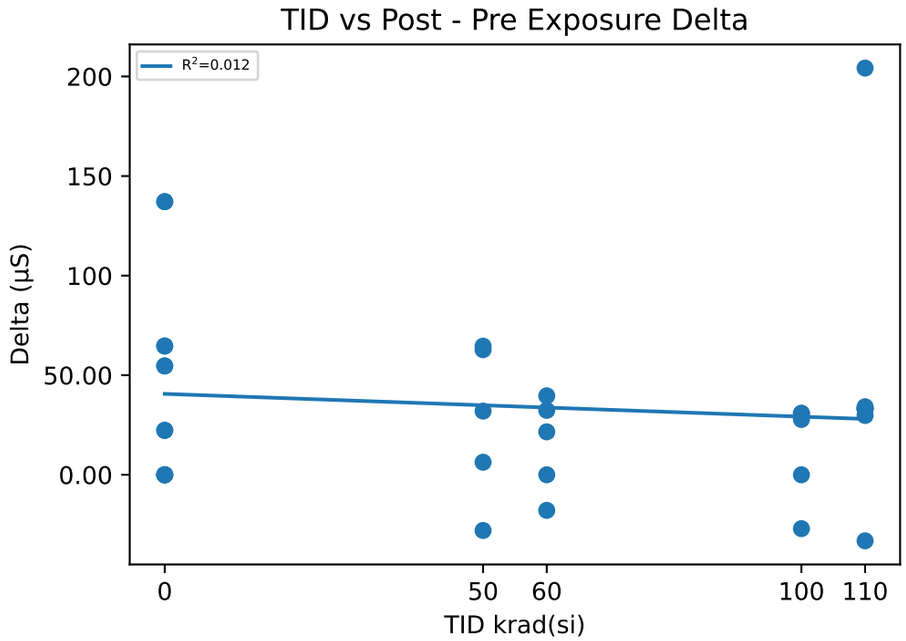
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.1398	-0.2107	-0.0709
2	0	CU2	-0.1553	-0.1857	-0.0304
3	0	CU3	-0.16	-0.1904	-0.0304
11	50	Unbiased-50k	-0.132	-0.1904	-0.0584
12	50	Unbiased-50k	-0.0775	-0.2107	-0.1332
13	50	Unbiased-50k	-0.1662	-0.1264	0.0398
14	50	Unbiased-50k	-0.1242	-0.1857	-0.0615
16	50	Unbiased-50k	-0.1009	-0.1889	-0.088
17	60	Biased-50k	-0.132	-0.167	-0.035
18	60	Biased-50k	-0.1071	-0.1686	-0.0615
19	60	Biased-50k	-0.1631	-0.1639	-0.0008
20	60	Biased-50k	-0.0915	-0.2279	-0.1364
21	60	Biased-50k	-0.1818	-0.1639	0.0179
24	100	Unbiased-100k	-0.1086	-0.4239	-0.3153
25	100	Unbiased-100k	-0.1444	-0.6908	-0.5464
26	100	Unbiased-100k	-0.0993	0.0896	0.1889
27	100	Unbiased-100k	-0.0868	-0.6471	-0.5603
28	100	Unbiased-100k	-0.1102	-0.683	-0.5728
29	110	Biased-100k	-0.0791	0.0163	0.0954
30	110	Biased-100k	-0.0946	0.2754	0.37
31	110	Biased-100k	-0.1429	0.316	0.4589
32	110	Biased-100k	-0.146	0.2582	0.4042
34	110	Biased-100k	-0.1662	0.3175	0.4837

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.16	-0.1517	-0.1398	0.01057	-0.2107	-0.1956	-0.1857	0.013286	-0.0709	-0.0439	-0.0304	0.023383
50	-0.1662	-0.12016	-0.0775	0.033418	-0.2107	-0.18042	-0.1264	0.031759	-0.1332	-0.06026	0.0398	0.063456
60	-0.1818	-0.1351	-0.0915	0.037615	-0.2279	-0.17826	-0.1639	0.027824	-0.1364	-0.04316	0.0179	0.060455
100	-0.1444	-0.10986	-0.0868	0.021436	-0.6908	-0.47104	0.0896	0.33195	-0.5728	-0.36118	0.1889	0.32536
110	-0.1662	-0.12576	-0.0791	0.037037	0.0163	0.23668	0.3175	0.12585	0.0954	0.36244	0.4837	0.15582

Device Test: 39.5 EA_GM(EA|Transconductance/VSNS1/7/7///90.9/634//0///@EA_GM)





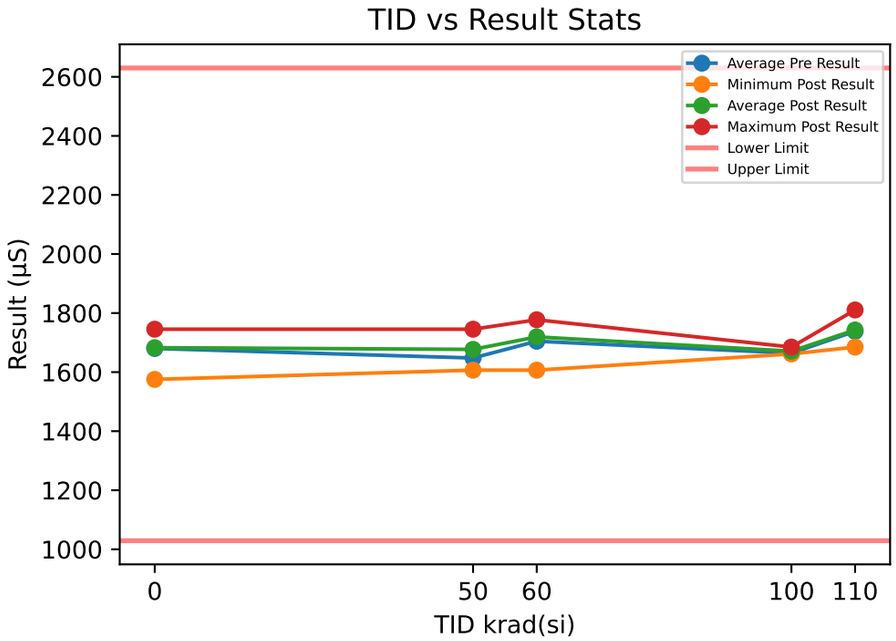
Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

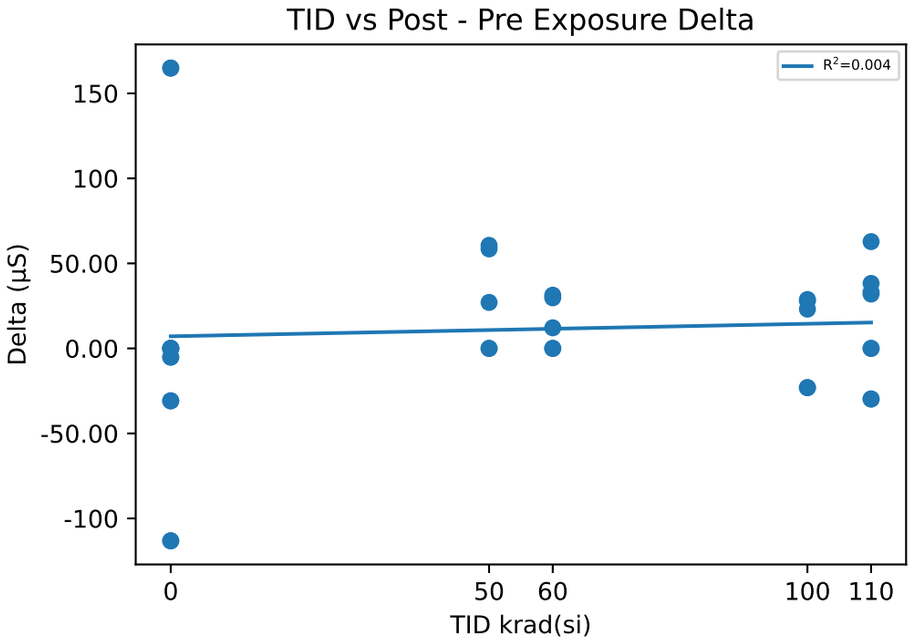
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1739.1	1739.1	0
2	0	CU2	1633.7	1656	22.303
3	0	CU3	1601.3	1601.3	0
11	50	Unbiased-50k	1661.7	1633.7	-27.974
12	50	Unbiased-50k	1745.3	1777.3	31.966
13	50	Unbiased-50k	1714.5	1777.3	62.802
14	50	Unbiased-50k	1745.3	1751.6	6.3009
16	50	Unbiased-50k	1656	1720.6	64.595
17	60	Biased-50k	1708.5	1690.6	-17.858
18	60	Biased-50k	1606.6	1628.2	21.566
19	60	Biased-50k	1714.5	1714.5	0
20	60	Biased-50k	1770.8	1810.5	39.645
21	60	Biased-50k	1601.3	1633.7	32.35
24	100	Unbiased-100k	1745.3	1745.3	0
25	100	Unbiased-100k	1714.5	1745.3	30.836
26	100	Unbiased-100k	1628.2	1656	27.785
27	100	Unbiased-100k	1633.7	1606.6	-27.048
28	100	Unbiased-100k	1714.5	1745.3	30.836
29	110	Biased-100k	1684.7	1714.5	29.766
30	110	Biased-100k	1803.7	1837.9	34.162
31	110	Biased-100k	1810.5	1777.3	-33.159
32	110	Biased-100k	1633.7	1837.9	204.21
34	110	Biased-100k	1777.3	1810.5	33.159

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1601.3	1658	1739.1	72.031	1601.3	1665.5	1739.1	69.362	0	7.4343	22.303	12.877
50	1656	1704.6	1745.3	43.659	1633.7	1732.1	1777.3	59.764	-27.974	27.538	64.595	39.272
60	1601.3	1680.4	1770.8	73.856	1628.2	1695.5	1810.5	74.081	-17.858	15.141	39.645	23.749
100	1628.2	1687.2	1745.3	52.952	1606.6	1699.7	1745.3	64.847	-27.048	12.482	30.836	25.624
110	1633.7	1742	1810.5	78.67	1714.5	1795.6	1837.9	51.745	-33.159	53.628	204.21	88.846

Device Test: 39.6 EA_GM(EA|Transconductance/VSNS2/7/7///90.9/634//0///@EA_GM)





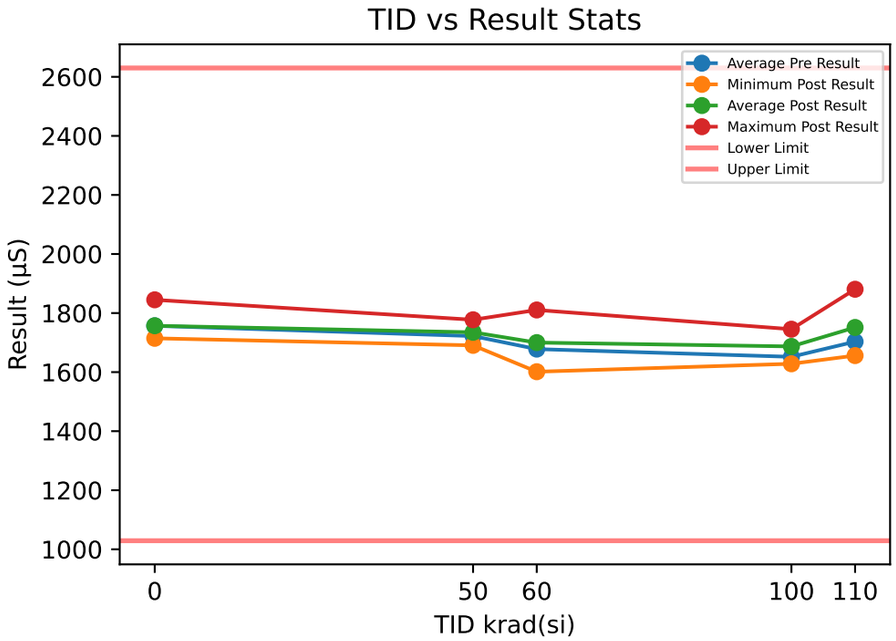
Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

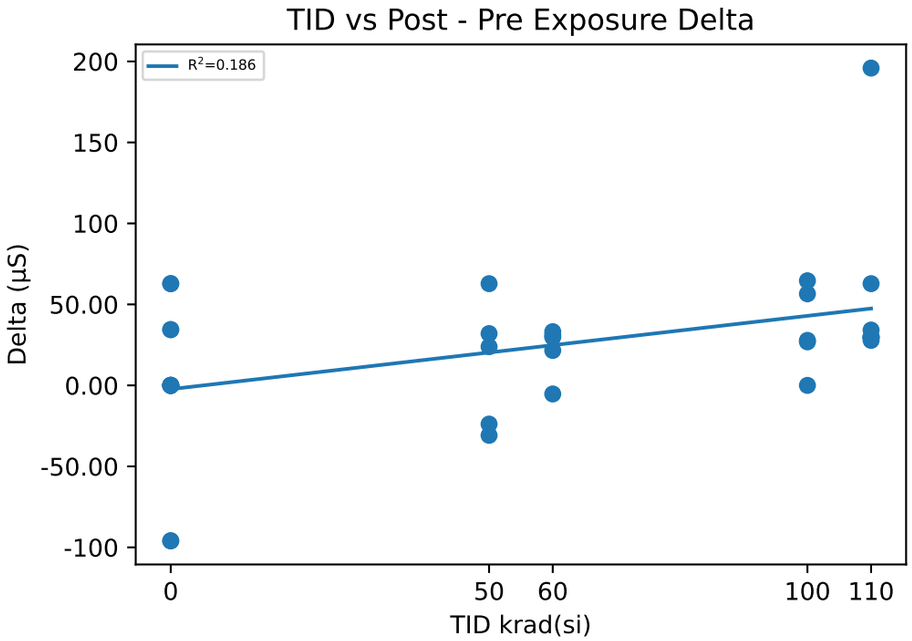
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1745.3	1745.3	0
2	0	CU2	1580.5	1575.3	-5.1314
3	0	CU3	1714.5	1714.5	0
11	50	Unbiased-50k	1606.6	1606.6	0
12	50	Unbiased-50k	1606.6	1633.7	27.048
13	50	Unbiased-50k	1684.7	1745.3	60.602
14	50	Unbiased-50k	1656	1714.5	58.515
16	50	Unbiased-50k	1684.7	1684.7	0
17	60	Biased-50k	1777.3	1777.3	0
18	60	Biased-50k	1575.3	1606.6	31.298
19	60	Biased-50k	1708.5	1720.6	12.117
20	60	Biased-50k	1777.3	1777.3	0
21	60	Biased-50k	1684.7	1714.5	29.766
24	100	Unbiased-100k	1684.7	1661.7	-23.079
25	100	Unbiased-100k	1661.7	1684.7	23.079
26	100	Unbiased-100k	1684.7	1661.7	-23.079
27	100	Unbiased-100k	1633.7	1661.7	27.974
28	100	Unbiased-100k	1656	1684.7	28.75
29	110	Biased-100k	1777.3	1810.5	33.159
30	110	Biased-100k	1739.1	1777.3	38.222
31	110	Biased-100k	1745.3	1777.3	31.966
32	110	Biased-100k	1714.5	1777.3	62.802
34	110	Biased-100k	1714.5	1714.5	0

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1580.5	1680.1	1745.3	87.652	1575.3	1678.4	1745.3	90.57	-5.1314	-1.7105	0	2.9626
50	1606.6	1647.7	1684.7	39.321	1606.6	1677	1745.3	56.929	0	29.233	60.602	29.814
60	1575.3	1704.6	1777.3	83.202	1606.6	1719.3	1777.3	69.726	0	14.636	31.298	15.34
100	1633.7	1664.2	1684.7	21.498	1661.7	1670.9	1684.7	12.641	-23.079	6.7291	28.75	27.297
110	1714.5	1738.1	1777.3	26	1714.5	1771.4	1810.5	34.885	0	33.23	62.802	22.39

Device Test: 39.7 EA_GM(EA|Transconductance/VSNS3/7/7///90.9/634//0///@EA_GM)





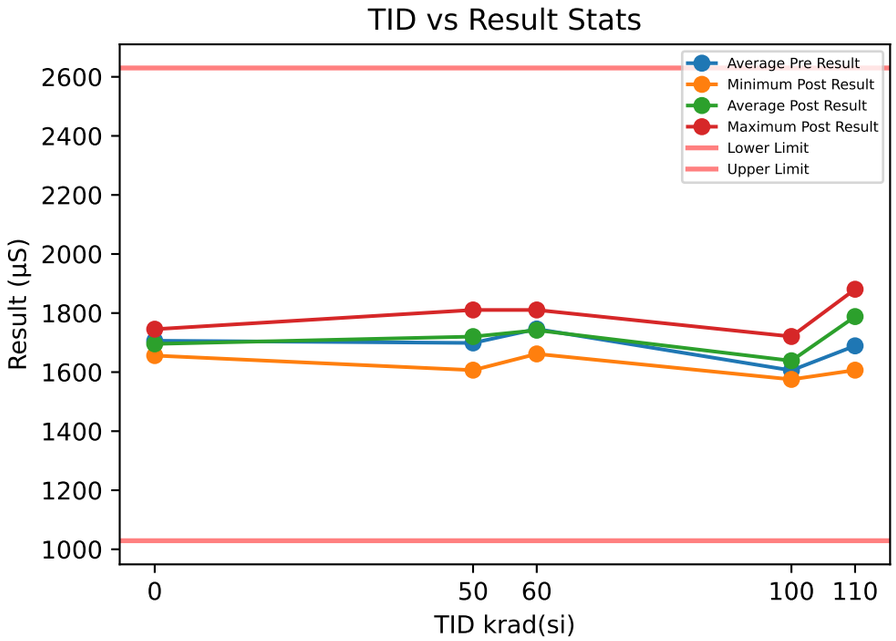
Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

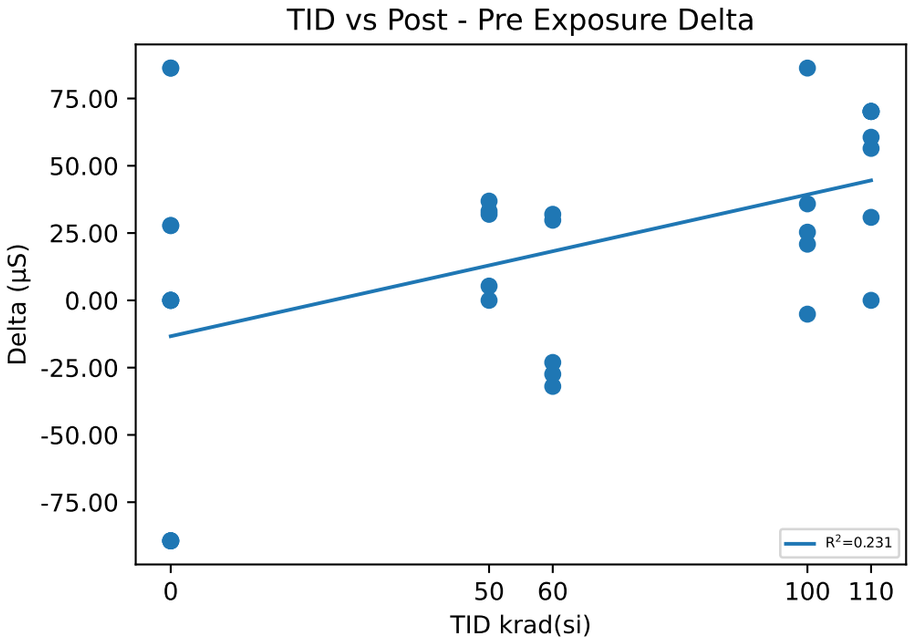
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1810.5	1844.9	34.419
2	0	CU2	1714.5	1714.5	0
3	0	CU3	1745.3	1745.3	0
11	50	Unbiased-50k	1690.6	1714.5	23.895
12	50	Unbiased-50k	1714.5	1690.6	-23.895
13	50	Unbiased-50k	1745.3	1714.5	-30.836
14	50	Unbiased-50k	1745.3	1777.3	31.966
16	50	Unbiased-50k	1714.5	1777.3	62.802
17	60	Biased-50k	1777.3	1810.5	33.159
18	60	Biased-50k	1606.6	1601.3	-5.3024
19	60	Biased-50k	1714.5	1745.3	30.836
20	60	Biased-50k	1684.7	1714.5	29.766
21	60	Biased-50k	1606.6	1628.2	21.566
24	100	Unbiased-100k	1601.3	1628.2	26.868
25	100	Unbiased-100k	1745.3	1745.3	0
26	100	Unbiased-100k	1628.2	1684.7	56.535
27	100	Unbiased-100k	1628.2	1656	27.785
28	100	Unbiased-100k	1656	1720.6	64.595
29	110	Biased-100k	1714.5	1777.3	62.802
30	110	Biased-100k	1803.7	1837.9	34.162
31	110	Biased-100k	1628.2	1656	27.785
32	110	Biased-100k	1684.7	1880.6	195.9
34	110	Biased-100k	1684.7	1714.5	29.766

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1714.5	1756.8	1810.5	48.991	1714.5	1768.2	1844.9	68.141	0	11.473	34.419	19.872
50	1690.6	1722.1	1745.3	23.384	1690.6	1734.8	1777.3	39.97	-30.836	12.786	62.802	39.501
60	1606.6	1678	1777.3	73.186	1601.3	1700	1810.5	85.671	-5.3024	22.005	33.159	15.879
100	1601.3	1651.8	1745.3	55.74	1628.2	1687	1745.3	47.316	0	35.157	64.595	25.897
110	1628.2	1703.2	1803.7	64.306	1656	1773.3	1880.6	90.732	27.785	70.083	195.9	71.742

Device Test: 39.8 EA_GM(EA|Transconductance/VSNS4/7/7///90.9/634//0///@EA_GM)





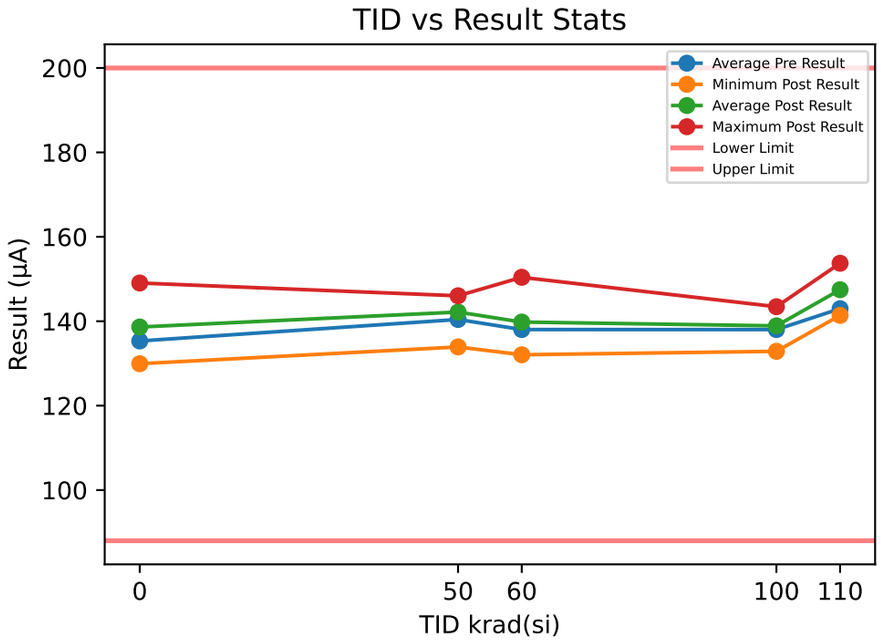
Test Results (Lower Limit = 1029.0, Upper Limit = 2630.0 (µS))

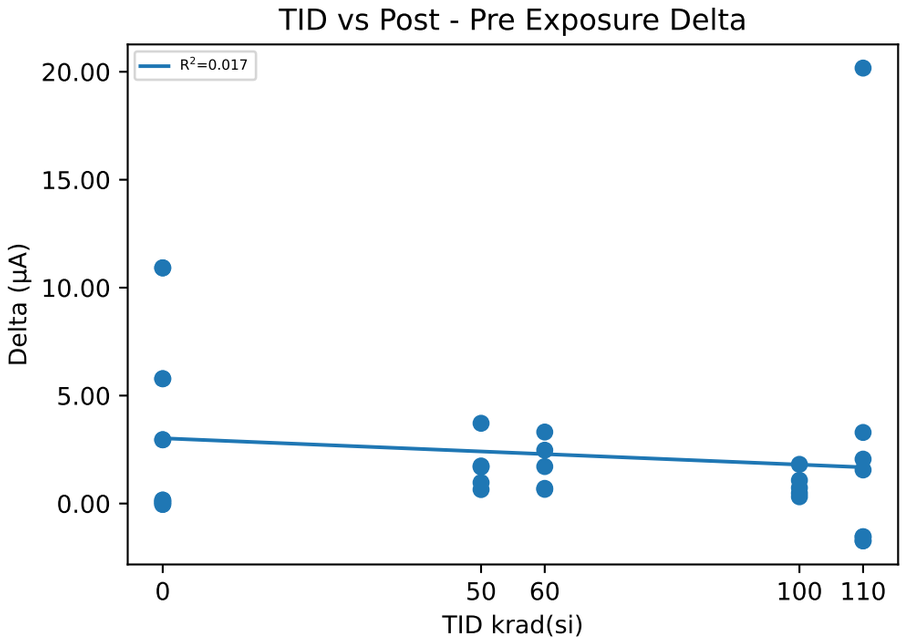
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1745.3	1745.3	0
2	0	CU2	1628.2	1656	27.785
3	0	CU3	1745.3	1745.3	0
11	50	Unbiased-50k	1661.7	1661.7	0
12	50	Unbiased-50k	1708.5	1745.3	36.873
13	50	Unbiased-50k	1601.3	1606.6	5.3024
14	50	Unbiased-50k	1777.3	1810.5	33.159
16	50	Unbiased-50k	1745.3	1777.3	31.966
17	60	Biased-50k	1777.3	1745.3	-31.966
18	60	Biased-50k	1837.9	1810.5	-27.431
19	60	Biased-50k	1684.7	1661.7	-23.079
20	60	Biased-50k	1745.3	1777.3	31.966
21	60	Biased-50k	1684.7	1714.5	29.766
24	100	Unbiased-100k	1628.2	1714.5	86.301
25	100	Unbiased-100k	1580.5	1575.3	-5.1314
26	100	Unbiased-100k	1555.1	1580.5	25.328
27	100	Unbiased-100k	1580.5	1601.3	20.864
28	100	Unbiased-100k	1684.7	1720.6	35.845
29	110	Biased-100k	1550.2	1606.6	56.463
30	110	Biased-100k	1714.5	1745.3	30.836
31	110	Biased-100k	1684.7	1684.7	0
32	110	Biased-100k	1684.7	1745.3	60.602
34	110	Biased-100k	1810.5	1880.6	70.173

Test Statistics (µS)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1628.2	1706.3	1745.3	67.629	1656	1715.6	1745.3	51.587	0	9.2617	27.785	16.042
50	1601.3	1698.8	1777.3	69.465	1606.6	1720.3	1810.5	84.208	0	21.46	36.873	17.367
60	1684.7	1746	1837.9	65.06	1661.7	1741.9	1810.5	57.349	-31.966	-4.1488	31.966	32.127
100	1555.1	1605.8	1684.7	51.435	1575.3	1638.4	1720.6	72.891	-5.1314	32.641	86.301	33.573
110	1550.2	1688.9	1810.5	93.157	1606.6	1732.5	1880.6	100.5	0	43.615	70.173	28.392

Device Test: 39.9 EA_SOURCE(EA|SourceCurrent/COMP1/7/7///90.9/634//0///@EA_SOURCE)





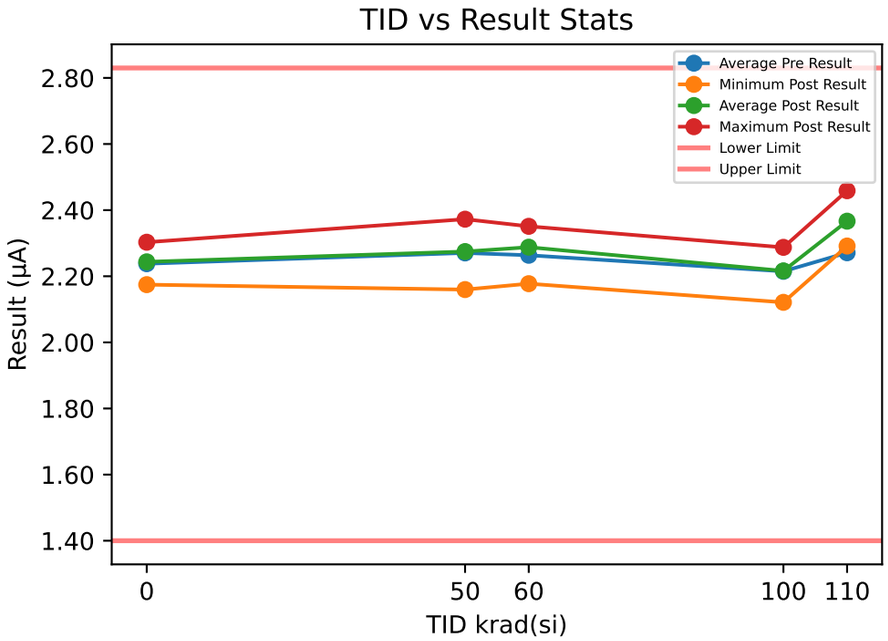
Test Results (Lower Limit = 88.0, Upper Limit = 200.0 (µA))

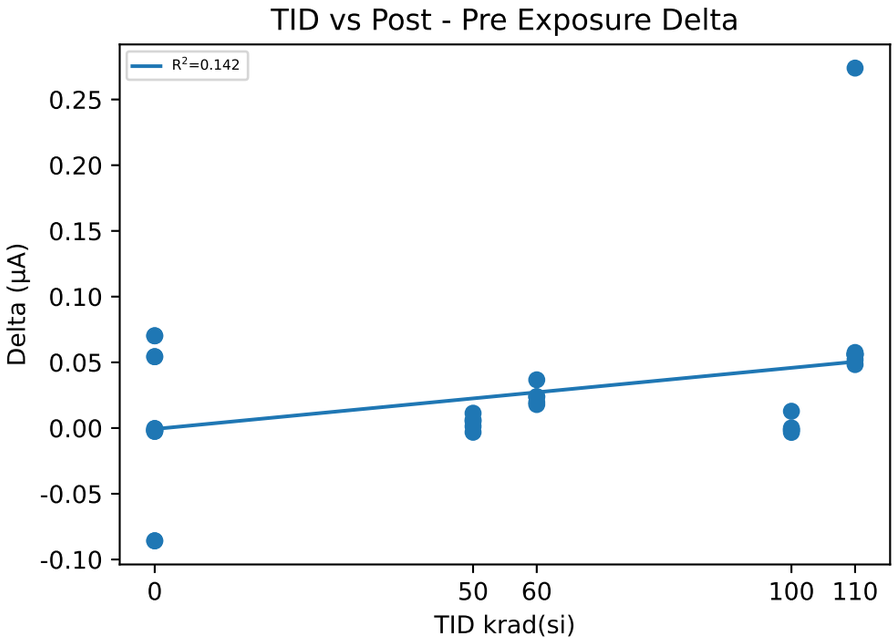
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	143.28	143.43	0.1583
2	0	CU2	132.73	132.79	0.0622
3	0	CU3	129.97	129.93	-0.0385
11	50	Unbiased-50k	133.26	133.91	0.6477
12	50	Unbiased-50k	144.95	145.92	0.9697
13	50	Unbiased-50k	142.31	146.03	3.7171
14	50	Unbiased-50k	142.61	144.35	1.7389
16	50	Unbiased-50k	138.96	140.66	1.695
17	60	Biased-50k	140.07	140.73	0.6576
18	60	Biased-50k	130.34	132.06	1.7133
19	60	Biased-50k	141.36	142.06	0.7012
20	60	Biased-50k	147.09	150.4	3.3117
21	60	Biased-50k	131.3	133.77	2.4707
24	100	Unbiased-100k	142.96	143.44	0.4786
25	100	Unbiased-100k	140.59	141.66	1.076
26	100	Unbiased-100k	132.05	133.86	1.8147
27	100	Unbiased-100k	132.56	132.87	0.3131
28	100	Unbiased-100k	141.96	142.69	0.7278
29	110	Biased-100k	139.83	141.39	1.5559
30	110	Biased-100k	147.69	150.98	3.2922
31	110	Biased-100k	145.66	147.71	2.0562
32	110	Biased-100k	133.56	153.74	20.172
34	110	Biased-100k	148.11	146.57	-1.5395

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	129.97	135.32	143.28	7.0224	129.93	135.38	143.43	7.1153	-0.0385	0.060667	0.1583	0.098409
50	133.26	140.42	144.95	4.5346	133.91	142.17	146.03	5.1043	0.6477	1.7537	3.7171	1.1934
60	130.34	138.03	147.09	7.1012	132.06	139.8	150.4	7.3262	0.6576	1.7709	3.3117	1.1457
100	132.05	138.02	142.96	5.293	132.87	138.91	143.44	5.1075	0.3131	0.88204	1.8147	0.59534
110	133.56	142.97	148.11	6.2091	141.39	148.08	153.74	4.6808	-1.5395	5.1073	20.172	8.6072

Device Test: 40.1 I_SS(SoftStart|ChargeCurrent/SS1/3/3///90.9/634//0///@I_SS)





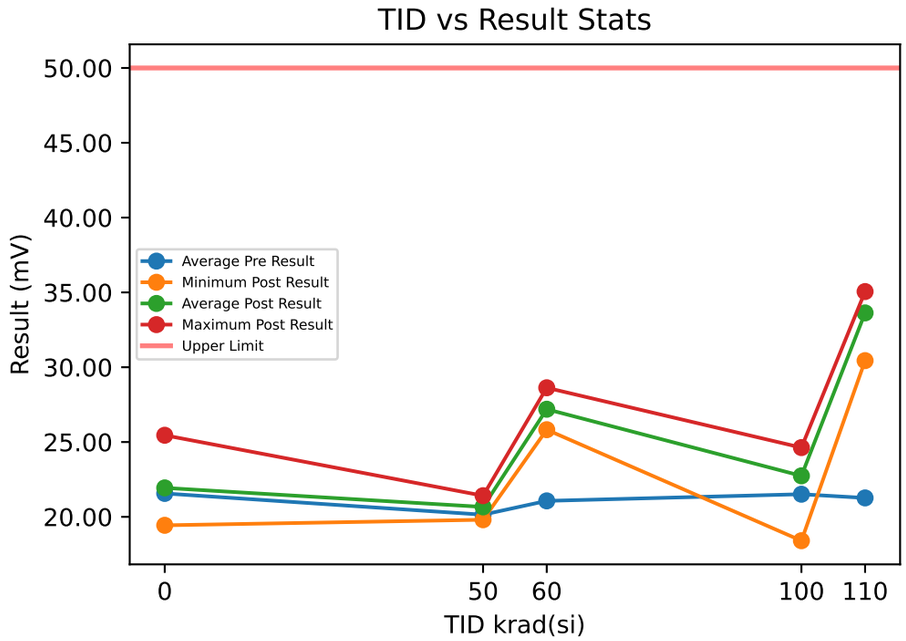
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

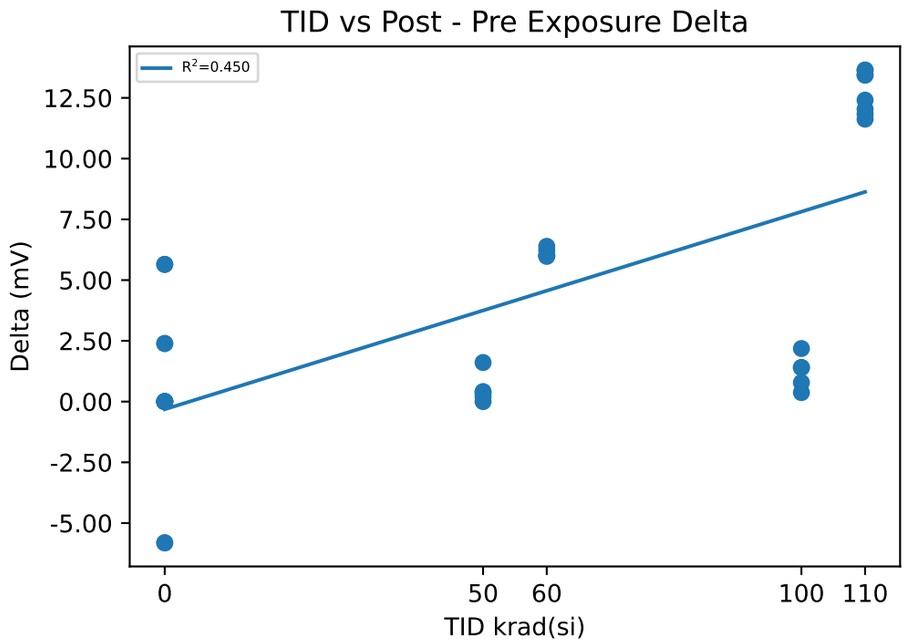
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3039	2.3022	-0.0017
2	0	CU2	2.2327	2.2323	-0.0004
3	0	CU3	2.1771	2.1746	-0.0025
11	50	Unbiased-50k	2.1546	2.1597	0.0051
12	50	Unbiased-50k	2.3521	2.3489	-0.0032
13	50	Unbiased-50k	2.2519	2.2532	0.0013
14	50	Unbiased-50k	2.3613	2.3726	0.0113
16	50	Unbiased-50k	2.2327	2.239	0.0063
17	60	Biased-50k	2.3033	2.3271	0.0238
18	60	Biased-50k	2.2885	2.3081	0.0196
19	60	Biased-50k	2.2519	2.2758	0.0239
20	60	Biased-50k	2.3143	2.351	0.0367
21	60	Biased-50k	2.1596	2.1775	0.0179
24	100	Unbiased-100k	2.2748	2.2715	-0.0033
25	100	Unbiased-100k	2.2746	2.2874	0.0128
26	100	Unbiased-100k	2.1417	2.1418	0.0001
27	100	Unbiased-100k	2.1225	2.1211	-0.0014
28	100	Unbiased-100k	2.261	2.2595	-0.0015
29	110	Biased-100k	2.2431	2.2914	0.0483
30	110	Biased-100k	2.3033	2.3608	0.0575
31	110	Biased-100k	2.3168	2.3688	0.052
32	110	Biased-100k	2.1848	2.4587	0.2739
34	110	Biased-100k	2.3073	2.363	0.0557

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1771	2.2379	2.3039	0.06356	2.1746	2.2364	2.3022	0.063897	-0.0025	-0.0015333	-0.0004	0.0010599
50	2.1546	2.2705	2.3613	0.086762	2.1597	2.2747	2.3726	0.086677	-0.0032	0.00416	0.0113	0.0054496
60	2.1596	2.2635	2.3143	0.062689	2.1775	2.2879	2.351	0.067566	0.0179	0.02438	0.0367	0.0073686
100	2.1225	2.2149	2.2748	0.076114	2.1211	2.2163	2.2874	0.078393	-0.0033	0.00134	0.0128	0.0065187
110	2.1848	2.2711	2.3168	0.056275	2.2914	2.3685	2.4587	0.059519	0.0483	0.09748	0.2739	0.098685

Device Test: 40.10 V_SS_START(SoftStart|MaxStartupVoltage/SS2/3/3///90.9/634//0///@V_SS_START)





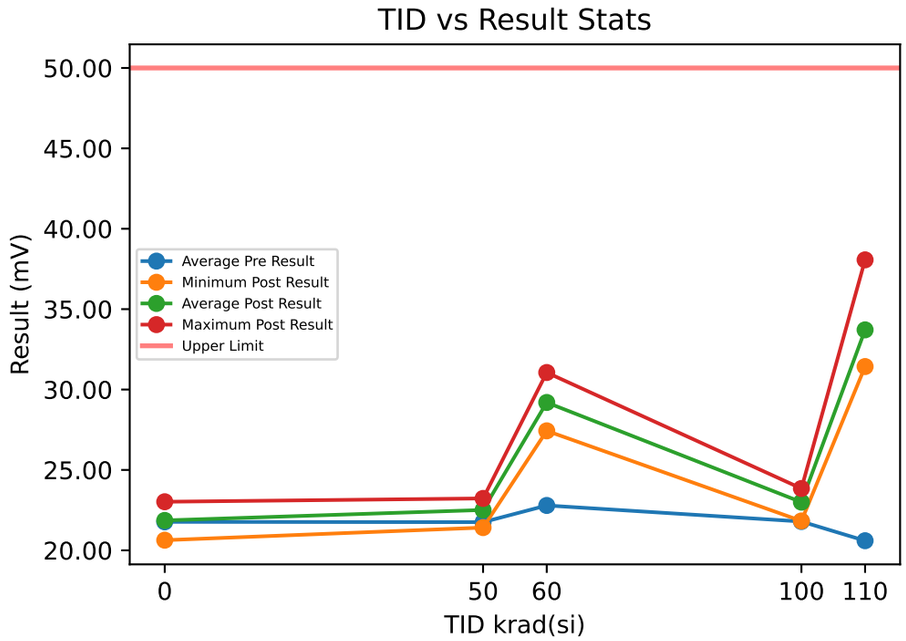
Test Results (Upper Limit = 50.0 (mV))

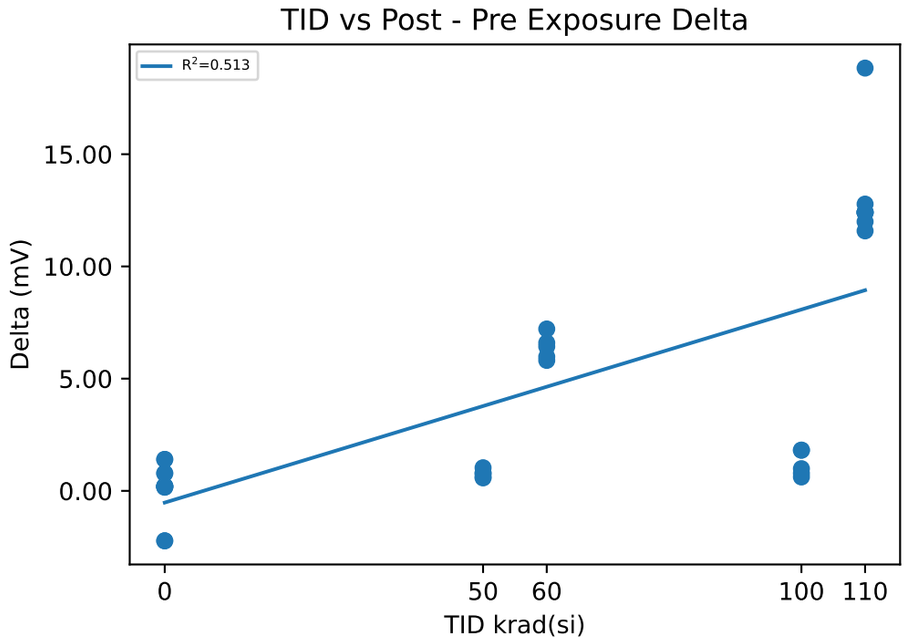
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	19.435	19.435	0
2	0	CU2	25.453	25.453	0
3	0	CU3	19.806	19.806	0
11	50	Unbiased-50k	21.414	21.414	0
12	50	Unbiased-50k	19.229	20.837	1.6076
13	50	Unbiased-50k	20.837	21.043	0.2061
14	50	Unbiased-50k	19.806	20.218	0.4122
16	50	Unbiased-50k	19.435	19.806	0.371
17	60	Biased-50k	22.65	28.627	5.9769
18	60	Biased-50k	21.62	27.638	6.0181
19	60	Biased-50k	20.012	26.236	6.2241
20	60	Biased-50k	19.806	25.824	6.018
21	60	Biased-50k	21.249	27.638	6.389
24	100	Unbiased-100k	21.826	23.227	1.4015
25	100	Unbiased-100k	22.238	23.021	0.7832
26	100	Unbiased-100k	23.021	24.423	1.4015
27	100	Unbiased-100k	22.444	24.629	2.1847
28	100	Unbiased-100k	18.034	18.405	0.371
29	110	Biased-100k	23.021	35.057	12.036
30	110	Biased-100k	22.444	34.851	12.407
31	110	Biased-100k	18.611	30.441	11.83
32	110	Biased-100k	22.032	33.656	11.624
34	110	Biased-100k	20.218	33.656	13.438

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.435	21.565	25.453	3.3726	19.435	21.565	25.453	3.3726	0	0	0	0
50	19.229	20.144	21.414	0.94148	19.806	20.663	21.414	0.64609	0	0.51938	1.6076	0.62961
60	19.806	21.067	22.65	1.1777	25.824	27.193	28.627	1.1447	5.9769	6.1252	6.389	0.1763
100	18.034	21.513	23.021	1.9919	18.405	22.741	24.629	2.5254	0.371	1.2284	2.1847	0.69061
110	18.611	21.265	23.021	1.8168	30.441	33.532	35.057	1.8475	11.624	12.267	13.438	0.71546

Device Test: 40.11 V_SS_START(SoftStart|MaxStartupVoltage/SS3/3/3///90.9/634//0///@V_SS_START)





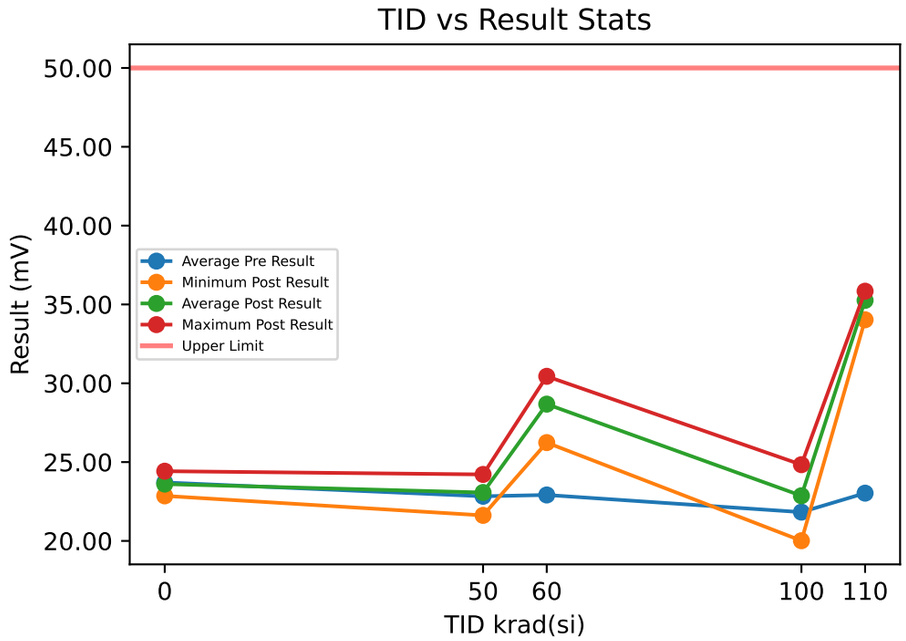
Test Results (Upper Limit = 50.0 (mV))

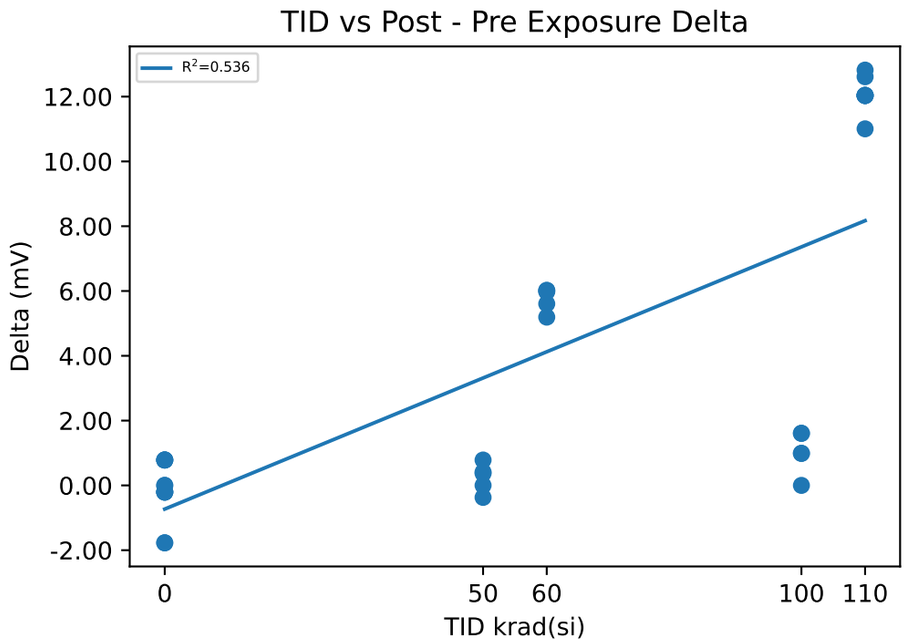
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	22.856	23.021	0.1649
2	0	CU2	21.62	21.826	0.2061
3	0	CU3	20.837	21.043	0.2061
11	50	Unbiased-50k	22.444	23.227	0.7832
12	50	Unbiased-50k	21.62	22.65	1.0305
13	50	Unbiased-50k	22.444	23.227	0.7832
14	50	Unbiased-50k	21.414	22.032	0.6183
16	50	Unbiased-50k	20.837	21.414	0.577
17	60	Biased-50k	21.826	28.421	6.5952
18	60	Biased-50k	22.444	28.421	5.9769
19	60	Biased-50k	21.62	27.432	5.812
20	60	Biased-50k	23.433	30.647	7.2135
21	60	Biased-50k	24.629	31.059	6.4302
24	100	Unbiased-100k	20.837	21.826	0.9892
25	100	Unbiased-100k	22.032	22.65	0.6183
26	100	Unbiased-100k	22.444	23.227	0.7832
27	100	Unbiased-100k	22.032	23.846	1.8137
28	100	Unbiased-100k	21.62	23.433	1.8137
29	110	Biased-100k	19.435	31.43	11.995
30	110	Biased-100k	22.856	35.634	12.778
31	110	Biased-100k	20.837	32.419	11.583
32	110	Biased-100k	19.229	38.066	18.837
34	110	Biased-100k	20.631	33.038	12.407

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.837	21.771	22.856	1.0183	21.043	21.963	23.021	0.99638	0.1649	0.19237	0.2061	0.023787
50	20.837	21.752	22.444	0.69426	21.414	22.51	23.227	0.7873	0.577	0.75844	1.0305	0.17875
60	21.62	22.79	24.629	1.2464	27.432	29.196	31.059	1.5724	5.812	6.4056	7.2135	0.55349
100	20.837	21.793	22.444	0.60885	21.826	22.996	23.846	0.78352	0.6183	1.2036	1.8137	0.57222
110	19.229	20.598	22.856	1.4478	31.43	34.118	38.066	2.7003	11.583	13.52	18.837	3.0059

Device Test: 40.12 V_SS_START(SoftStart|MaxStartupVoltage/SS4/3/3///90.9/634//0///@V_SS_START)





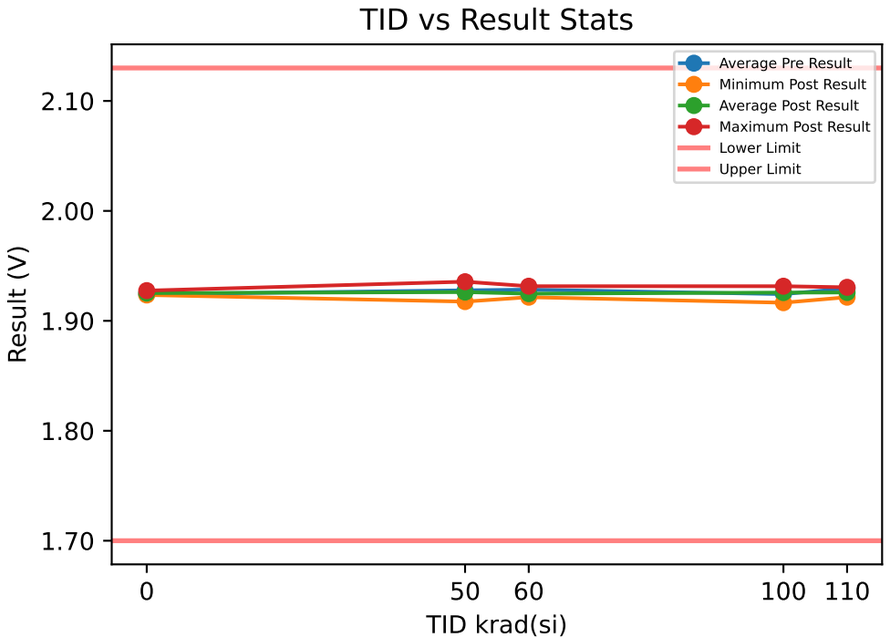
Test Results (Upper Limit = 50.0 (mV))

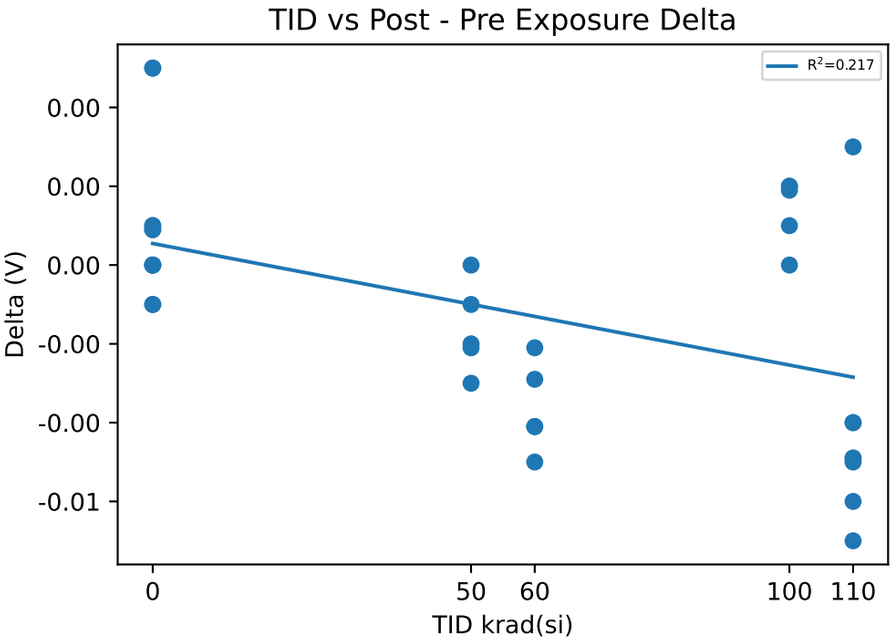
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	23.64	23.433	-0.2061
2	0	CU2	22.856	22.856	0
3	0	CU3	24.629	24.423	-0.2061
11	50	Unbiased-50k	21.62	21.62	0
12	50	Unbiased-50k	23.433	24.217	0.7832
13	50	Unbiased-50k	23.227	23.64	0.4122
14	50	Unbiased-50k	23.227	22.856	-0.371
16	50	Unbiased-50k	22.65	23.021	0.371
17	60	Biased-50k	24.423	30.029	5.6059
18	60	Biased-50k	21.043	26.236	5.1936
19	60	Biased-50k	24.423	30.441	6.0181
20	60	Biased-50k	22.856	28.833	5.9769
21	60	Biased-50k	21.826	27.844	6.0181
24	100	Unbiased-100k	20.837	21.826	0.9892
25	100	Unbiased-100k	23.64	24.629	0.9893
26	100	Unbiased-100k	23.227	24.835	1.6076
27	100	Unbiased-100k	20.012	20.012	0
28	100	Unbiased-100k	21.414	23.021	1.6076
29	110	Biased-100k	23.021	35.057	12.036
30	110	Biased-100k	23.227	35.84	12.613
31	110	Biased-100k	22.444	35.264	12.819
32	110	Biased-100k	23.021	34.027	11.006
34	110	Biased-100k	23.433	35.47	12.036

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.856	23.708	24.629	0.88824	22.856	23.571	24.423	0.79219	-0.2061	-0.1374	0	0.11899
50	21.62	22.832	23.433	0.73772	21.62	23.071	24.217	0.97345	-0.371	0.23908	0.7832	0.43954
60	21.043	22.914	24.423	1.52	26.236	28.677	30.441	1.7039	5.1936	5.7625	6.0181	0.36222
100	20.012	21.826	23.64	1.5565	20.012	22.865	24.835	2.0146	0	1.0387	1.6076	0.65785
110	22.444	23.029	23.433	0.36915	34.027	35.132	35.84	0.68192	11.006	12.102	12.819	0.70472

Device Test: 40.13 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP1/3/3///90.9/634//0///@COMP_V_CLAMP)





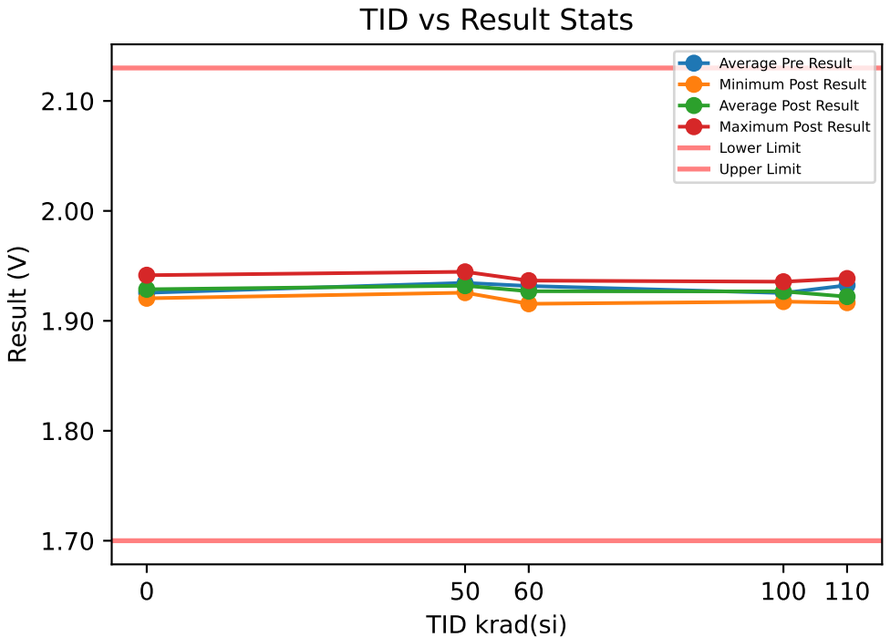
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

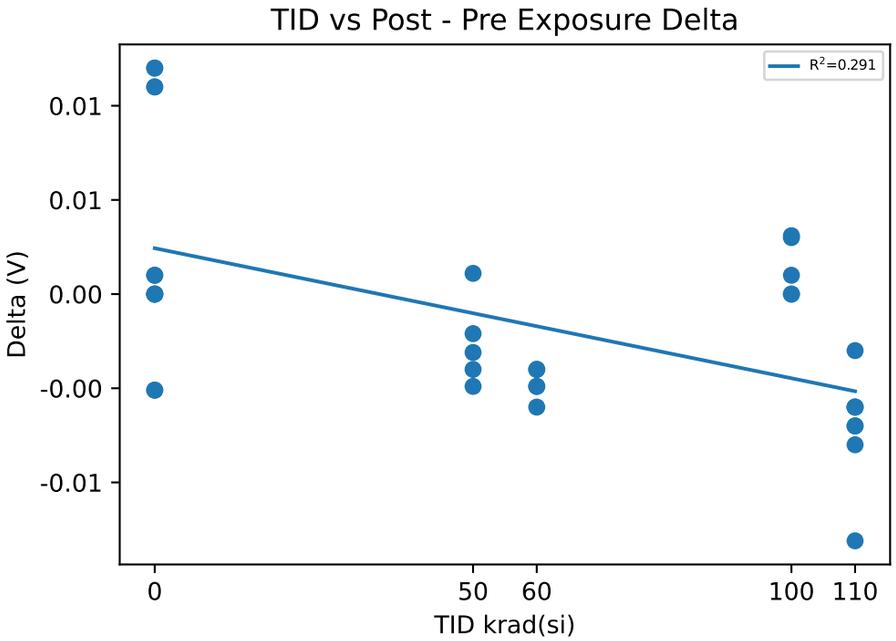
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9256	1.9265	0.0009
2	0	CU2	1.9225	1.9235	0.001
3	0	CU3	1.9246	1.9246	0
11	50	Unbiased-50k	1.9205	1.9175	-0.003
12	50	Unbiased-50k	1.9336	1.9315	-0.0021
13	50	Unbiased-50k	1.9376	1.9356	-0.002
14	50	Unbiased-50k	1.9256	1.9256	0
16	50	Unbiased-50k	1.9215	1.9205	-0.001
17	60	Biased-50k	1.9275	1.9246	-0.0029
18	60	Biased-50k	1.9356	1.9315	-0.0041
19	60	Biased-50k	1.9256	1.9215	-0.0041
20	60	Biased-50k	1.9285	1.9235	-0.005
21	60	Biased-50k	1.9246	1.9225	-0.0021
24	100	Unbiased-100k	1.9295	1.9315	0.002
25	100	Unbiased-100k	1.9285	1.9295	0.001
26	100	Unbiased-100k	1.9215	1.9215	0
27	100	Unbiased-100k	1.9146	1.9165	0.0019
28	100	Unbiased-100k	1.9275	1.9295	0.002
29	110	Biased-100k	1.9275	1.9215	-0.006
30	110	Biased-100k	1.9315	1.9265	-0.005
31	110	Biased-100k	1.9305	1.9235	-0.007
32	110	Biased-100k	1.9275	1.9305	0.003
34	110	Biased-100k	1.9305	1.9265	-0.004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9225	1.9242	1.9256	0.0015822	1.9235	1.9249	1.9265	0.0015177	0	0.00063333	0.001	0.00055076
50	1.9205	1.9278	1.9376	0.0075414	1.9175	1.9261	1.9356	0.0074995	-0.003	-0.00162	0	0.0011498
60	1.9246	1.9284	1.9356	0.0043282	1.9215	1.9247	1.9315	0.0039613	-0.005	-0.00364	-0.0021	0.0011393
100	1.9146	1.9243	1.9295	0.0062619	1.9165	1.9257	1.9315	0.0064187	0	0.00138	0.002	0.00087864
110	1.9275	1.9295	1.9315	0.0018708	1.9215	1.9257	1.9305	0.0034205	-0.007	-0.0038	0.003	0.0039623

Device Test: 40.14 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP2/3/3///90.9/634//0///@COMP_V_CLAMP)





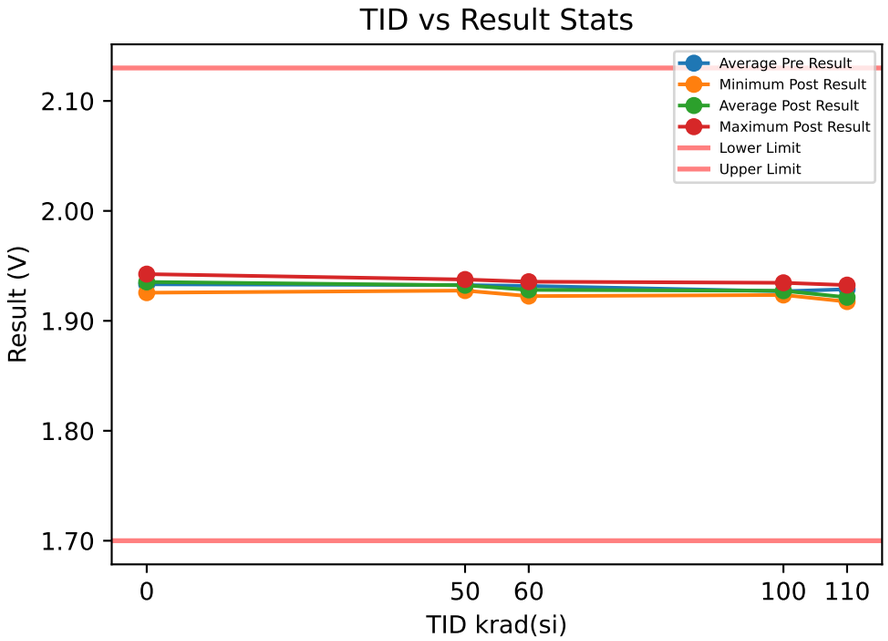
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

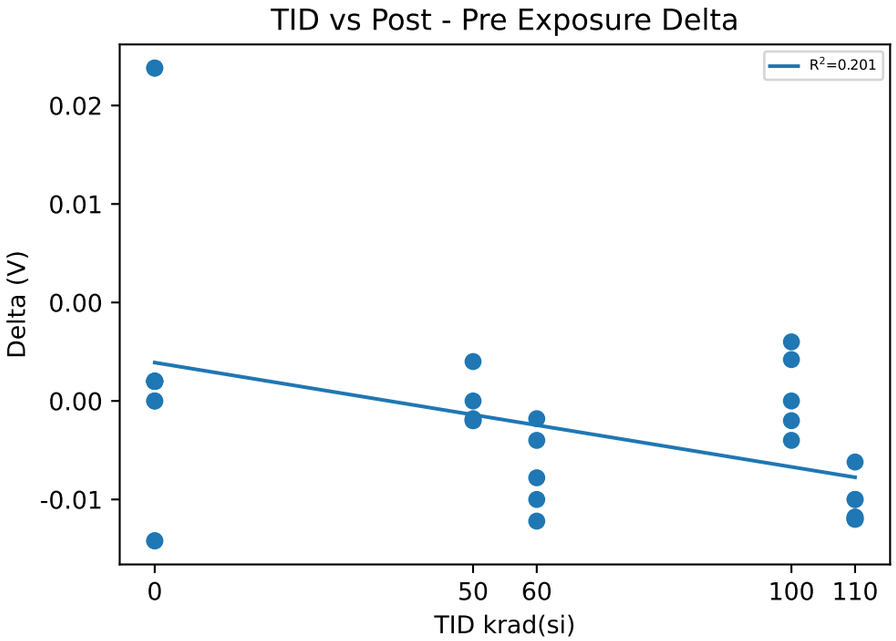
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9305	1.9315	0.001
2	0	CU2	1.9205	1.9205	0
3	0	CU3	1.9256	1.9256	0
11	50	Unbiased-50k	1.9315	1.9275	-0.004
12	50	Unbiased-50k	1.9336	1.9305	-0.0031
13	50	Unbiased-50k	1.9435	1.9446	0.0011
14	50	Unbiased-50k	1.9336	1.9315	-0.0021
16	50	Unbiased-50k	1.9305	1.9256	-0.0049
17	60	Biased-50k	1.9325	1.9285	-0.004
18	60	Biased-50k	1.9415	1.9366	-0.0049
19	60	Biased-50k	1.9305	1.9256	-0.0049
20	60	Biased-50k	1.9325	1.9285	-0.004
21	60	Biased-50k	1.9215	1.9155	-0.006
24	100	Unbiased-100k	1.9235	1.9265	0.003
25	100	Unbiased-100k	1.9356	1.9356	0
26	100	Unbiased-100k	1.9305	1.9336	0.0031
27	100	Unbiased-100k	1.9195	1.9205	0.001
28	100	Unbiased-100k	1.9175	1.9175	0
29	110	Biased-100k	1.9295	1.9235	-0.006
30	110	Biased-100k	1.9415	1.9385	-0.003
31	110	Biased-100k	1.9336	1.9256	-0.008
32	110	Biased-100k	1.9336	1.9205	-0.0131
34	110	Biased-100k	1.9235	1.9175	-0.006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9205	1.9255	1.9305	0.0050003	1.9205	1.9259	1.9315	0.0055048	0	0.00033333	0.001	0.00057735
50	1.9305	1.9345	1.9435	0.0051868	1.9256	1.9319	1.9446	0.0074574	-0.0049	-0.0026	0.0011	0.0023152
60	1.9215	1.9317	1.9415	0.0071204	1.9155	1.9269	1.9366	0.0075969	-0.006	-0.00476	-0.004	0.00082644
100	1.9175	1.9253	1.9356	0.0075968	1.9175	1.9267	1.9356	0.0079046	0	0.00142	0.0031	0.0015434
110	1.9235	1.9323	1.9415	0.006582	1.9175	1.9251	1.9385	0.0080822	-0.0131	-0.00722	-0.003	0.0037406

Device Test: 40.15 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP3/3/3///90.9/634//0///@COMP_V_CLAMP)





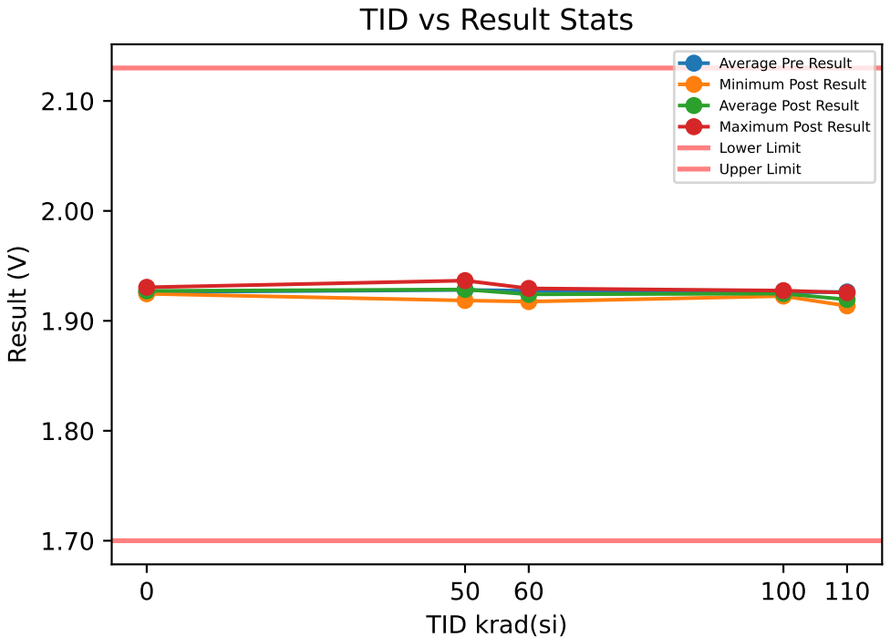
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

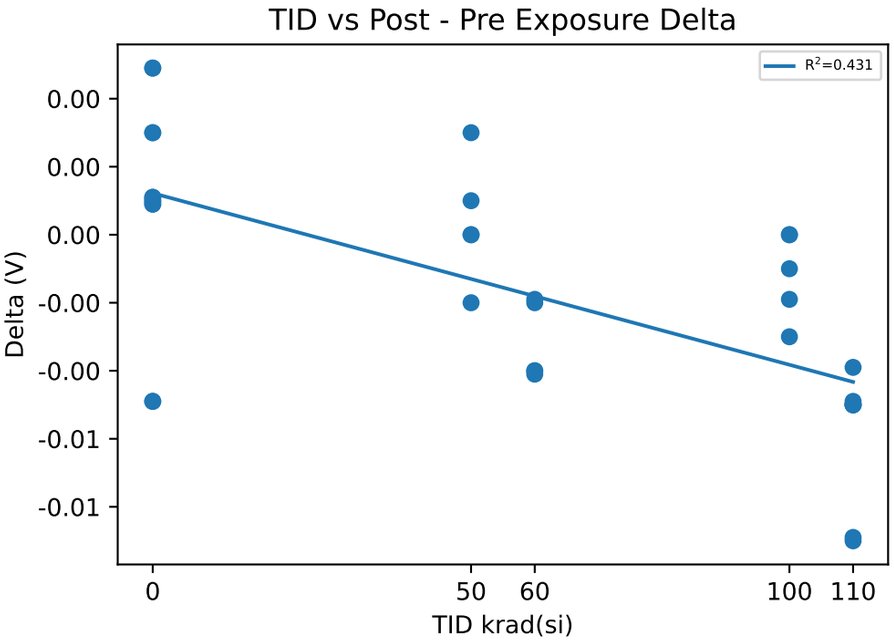
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9405	1.9415	0.001
2	0	CU2	1.9256	1.9256	0
3	0	CU3	1.9336	1.9346	0.001
11	50	Unbiased-50k	1.9305	1.9325	0.002
12	50	Unbiased-50k	1.9285	1.9275	-0.001
13	50	Unbiased-50k	1.9385	1.9376	-0.0009
14	50	Unbiased-50k	1.9346	1.9346	0
16	50	Unbiased-50k	1.9305	1.9295	-0.001
17	60	Biased-50k	1.9305	1.9285	-0.002
18	60	Biased-50k	1.9275	1.9225	-0.005
19	60	Biased-50k	1.9395	1.9356	-0.0039
20	60	Biased-50k	1.9346	1.9285	-0.0061
21	60	Biased-50k	1.9265	1.9256	-0.0009
24	100	Unbiased-100k	1.9235	1.9235	0
25	100	Unbiased-100k	1.9356	1.9346	-0.001
26	100	Unbiased-100k	1.9285	1.9265	-0.002
27	100	Unbiased-100k	1.9235	1.9265	0.003
28	100	Unbiased-100k	1.9235	1.9256	0.0021
29	110	Biased-100k	1.9305	1.9246	-0.0059
30	110	Biased-100k	1.9356	1.9325	-0.0031
31	110	Biased-100k	1.9235	1.9175	-0.006
32	110	Biased-100k	1.9305	1.9246	-0.0059
34	110	Biased-100k	1.9235	1.9185	-0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9256	1.9332	1.9405	0.0074568	1.9256	1.9339	1.9415	0.0079731	0	0.00066667	0.001	0.00057735
50	1.9285	1.9325	1.9385	0.0040127	1.9275	1.9323	1.9376	0.0040091	-0.001	-0.00018	0.002	0.0012892
60	1.9265	1.9317	1.9395	0.0053705	1.9225	1.9281	1.9356	0.0048521	-0.0061	-0.00358	-0.0009	0.00213
100	1.9235	1.9269	1.9356	0.0053134	1.9235	1.9273	1.9346	0.0042395	-0.002	0.00042	0.003	0.0020933
110	1.9235	1.9287	1.9356	0.0052002	1.9175	1.9235	1.9325	0.0060086	-0.006	-0.00518	-0.0031	0.0012317

Device Test: 40.16 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP4/3/3///90.9/634//0///@COMP_V_CLAMP)





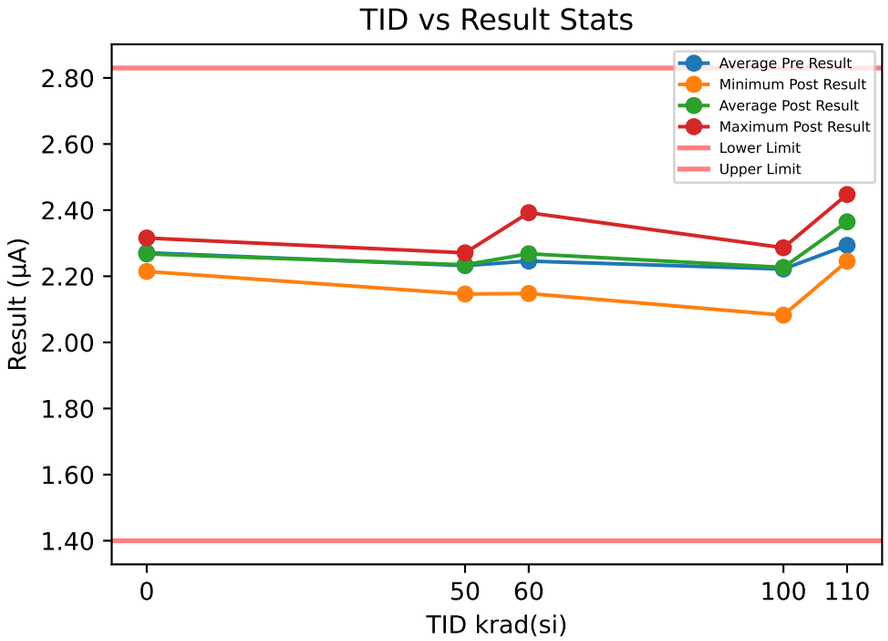
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

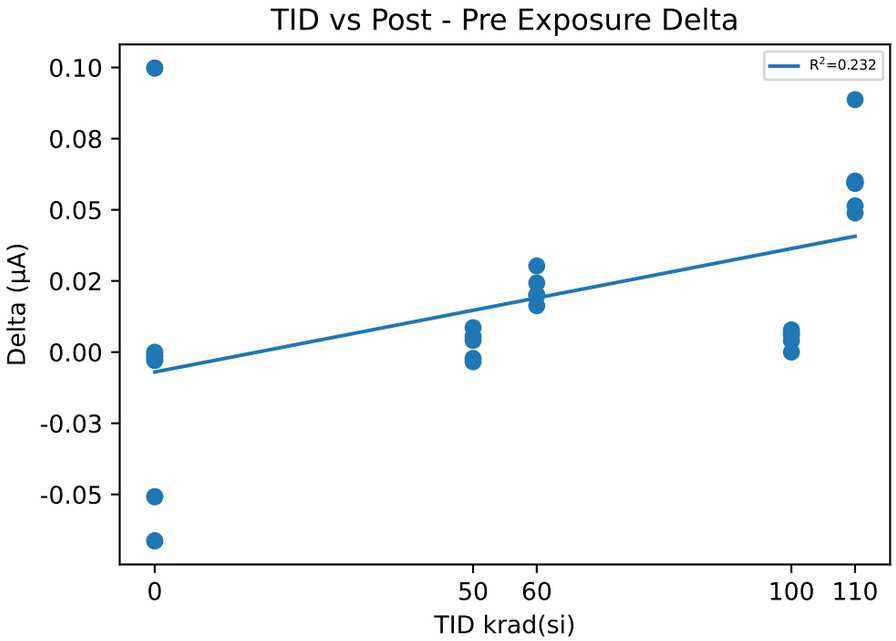
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9256	1.9265	0.0009
2	0	CU2	1.9235	1.9246	0.0011
3	0	CU3	1.9295	1.9305	0.001
11	50	Unbiased-50k	1.9295	1.9275	-0.002
12	50	Unbiased-50k	1.9305	1.9305	0
13	50	Unbiased-50k	1.9295	1.9295	0
14	50	Unbiased-50k	1.9336	1.9366	0.003
16	50	Unbiased-50k	1.9175	1.9185	0.001
17	60	Biased-50k	1.9225	1.9205	-0.002
18	60	Biased-50k	1.9336	1.9295	-0.0041
19	60	Biased-50k	1.9215	1.9175	-0.004
20	60	Biased-50k	1.9315	1.9275	-0.004
21	60	Biased-50k	1.9275	1.9256	-0.0019
24	100	Unbiased-100k	1.9265	1.9235	-0.003
25	100	Unbiased-100k	1.9246	1.9246	0
26	100	Unbiased-100k	1.9275	1.9256	-0.0019
27	100	Unbiased-100k	1.9225	1.9225	0
28	100	Unbiased-100k	1.9285	1.9275	-0.001
29	110	Biased-100k	1.9265	1.9175	-0.009
30	110	Biased-100k	1.9285	1.9246	-0.0039
31	110	Biased-100k	1.9225	1.9136	-0.0089
32	110	Biased-100k	1.9305	1.9256	-0.0049
34	110	Biased-100k	1.9235	1.9185	-0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9235	1.9262	1.9295	0.0030447	1.9246	1.9272	1.9305	0.0030116	0.0009	0.001	0.0011	0.0001
50	1.9175	1.9281	1.9336	0.0061703	1.9185	1.9285	1.9366	0.00655	-0.002	0.0004	0.003	0.0018166
60	1.9215	1.9273	1.9336	0.0053397	1.9175	1.9241	1.9295	0.0049872	-0.0041	-0.0032	-0.0019	0.0011424
100	1.9225	1.9259	1.9285	0.0023942	1.9225	1.9247	1.9275	0.0019321	-0.003	-0.00118	0	0.0012892
110	1.9225	1.9263	1.9305	0.0033466	1.9136	1.92	1.9256	0.0050491	-0.009	-0.00634	-0.0039	0.0024214

Device Test: 40.2 I_SS(SoftStart|ChargeCurrent/SS2/3/3///90.9/634//0///@I_SS)





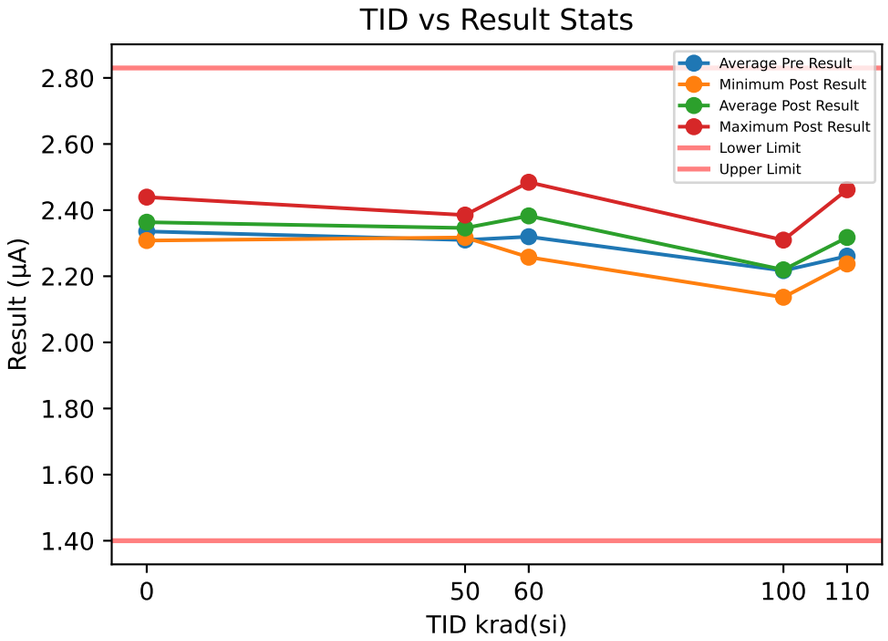
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

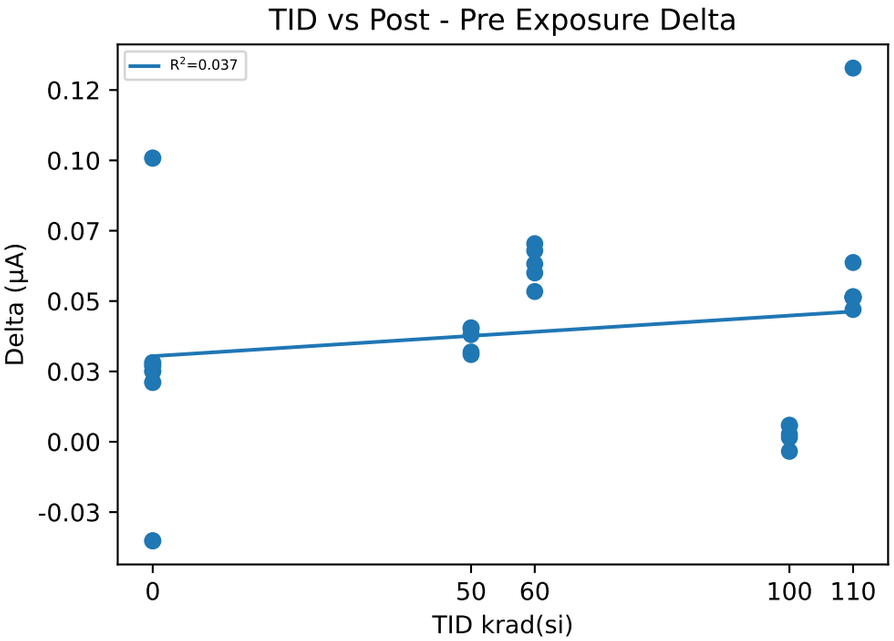
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3172	2.3157	-0.0015
2	0	CU2	2.2157	2.2156	-0.0001
3	0	CU3	2.2808	2.2779	-0.0029
11	50	Unbiased-50k	2.2523	2.2564	0.0041
12	50	Unbiased-50k	2.1496	2.1462	-0.0034
13	50	Unbiased-50k	2.2652	2.2708	0.0056
14	50	Unbiased-50k	2.251	2.2596	0.0086
16	50	Unbiased-50k	2.2426	2.2404	-0.0022
17	60	Biased-50k	2.218	2.2483	0.0303
18	60	Biased-50k	2.2151	2.2351	0.02
19	60	Biased-50k	2.368	2.3923	0.0243
20	60	Biased-50k	2.3004	2.3167	0.0163
21	60	Biased-50k	2.1277	2.1478	0.0201
24	100	Unbiased-100k	2.2259	2.2259	0
25	100	Unbiased-100k	2.2566	2.2632	0.0066
26	100	Unbiased-100k	2.2822	2.2862	0.004
27	100	Unbiased-100k	2.0762	2.0823	0.0061
28	100	Unbiased-100k	2.268	2.2758	0.0078
29	110	Biased-100k	2.1964	2.2453	0.0489
30	110	Biased-100k	2.3959	2.4473	0.0514
31	110	Biased-100k	2.2907	2.3508	0.0601
32	110	Biased-100k	2.2641	2.3528	0.0887
34	110	Biased-100k	2.3204	2.3797	0.0593

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2157	2.2712	2.3172	0.051422	2.2156	2.2697	2.3157	0.050547	-0.0029	-0.0015	-0.0001	0.0014
50	2.1496	2.2321	2.2652	0.046844	2.1462	2.2347	2.2708	0.050643	-0.0034	0.00254	0.0086	0.0051544
60	2.1277	2.2458	2.368	0.09162	2.1478	2.268	2.3923	0.091843	0.0163	0.0222	0.0303	0.0053404
100	2.0762	2.2218	2.2822	0.083979	2.0823	2.2267	2.2862	0.083868	0	0.0049	0.0078	0.0030643
110	2.1964	2.2935	2.3959	0.073331	2.2453	2.3552	2.4473	0.072777	0.0489	0.06168	0.0887	0.015869

Device Test: 40.3 I_SS(SoftStart|ChargeCurrent/SS3/3/3///90.9/634//0///@I_SS)





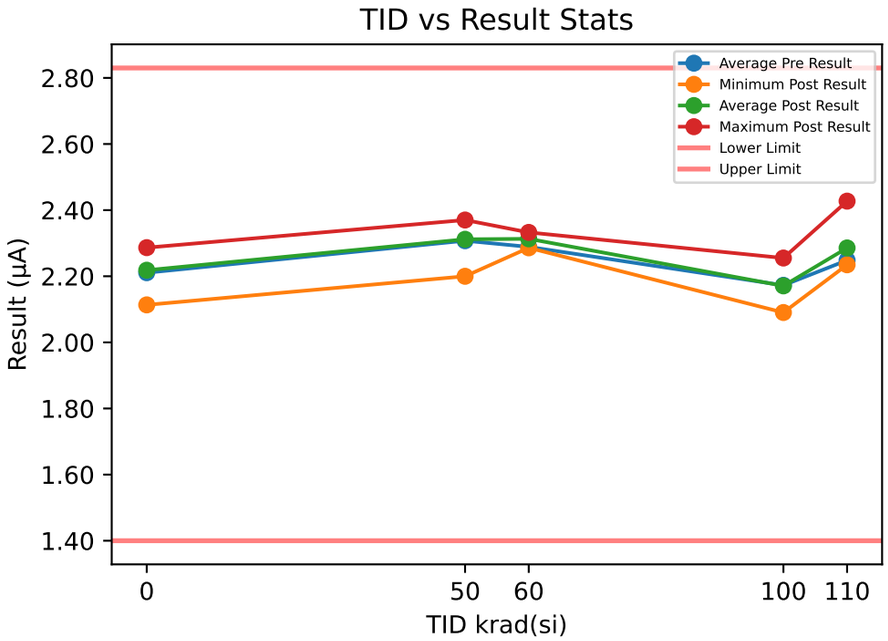
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

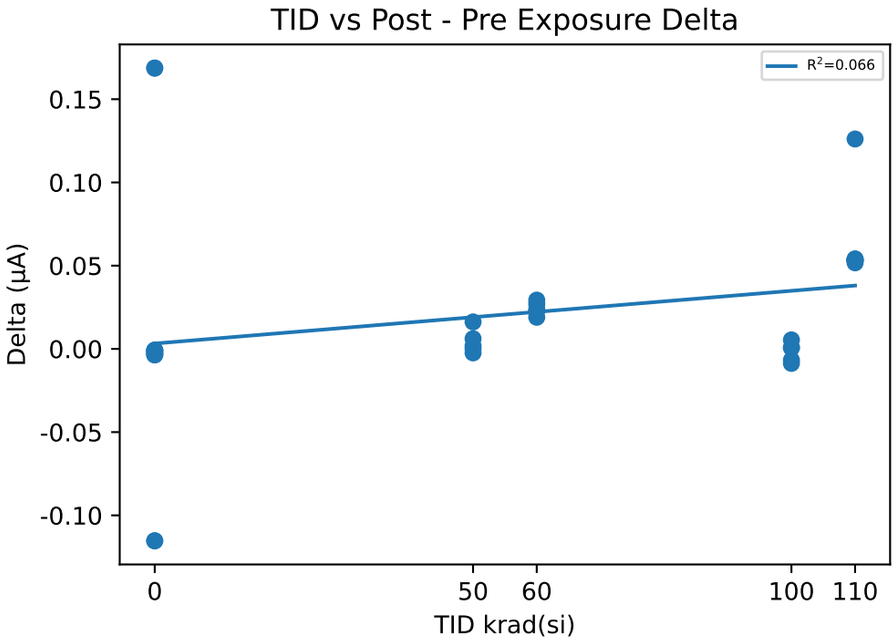
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4112	2.4393	0.0281
2	0	CU2	2.3088	2.3357	0.0269
3	0	CU3	2.2869	2.3119	0.025
11	50	Unbiased-50k	2.277	2.3173	0.0403
12	50	Unbiased-50k	2.2986	2.3367	0.0381
13	50	Unbiased-50k	2.2874	2.3193	0.0319
14	50	Unbiased-50k	2.3311	2.3716	0.0405
16	50	Unbiased-50k	2.3541	2.3851	0.031
17	60	Biased-50k	2.3963	2.4667	0.0704
18	60	Biased-50k	2.2487	2.3021	0.0534
19	60	Biased-50k	2.4211	2.4843	0.0632
20	60	Biased-50k	2.3343	2.4022	0.0679
21	60	Biased-50k	2.1976	2.2576	0.06
24	100	Unbiased-100k	2.175	2.1716	-0.0034
25	100	Unbiased-100k	2.3079	2.3094	0.0015
26	100	Unbiased-100k	2.1826	2.1883	0.0057
27	100	Unbiased-100k	2.1305	2.1364	0.0059
28	100	Unbiased-100k	2.2891	2.2918	0.0027
29	110	Biased-100k	2.1939	2.2454	0.0515
30	110	Biased-100k	2.3979	2.4616	0.0637
31	110	Biased-100k	2.1902	2.2372	0.047
32	110	Biased-100k	2.2781	2.4109	0.1328
34	110	Biased-100k	2.2445	2.2957	0.0512

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2869	2.3356	2.4112	0.066352	2.3119	2.3623	2.4393	0.067737	0.025	0.026667	0.0281	0.0015631
50	2.277	2.3096	2.3541	0.03209	2.3173	2.346	2.3851	0.030851	0.031	0.03636	0.0405	0.0045911
60	2.1976	2.3196	2.4211	0.095279	2.2576	2.3826	2.4843	0.099881	0.0534	0.06298	0.0704	0.0067076
100	2.1305	2.217	2.3079	0.077283	2.1364	2.2195	2.3094	0.07662	-0.0034	0.00248	0.0059	0.0037963
110	2.1902	2.2609	2.3979	0.084884	2.2372	2.3302	2.4616	0.10101	0.047	0.06924	0.1328	0.036074

Device Test: 40.4 I_SS(SoftStart|ChargeCurrent/SS4/3/3///90.9/634//0///@I_SS)





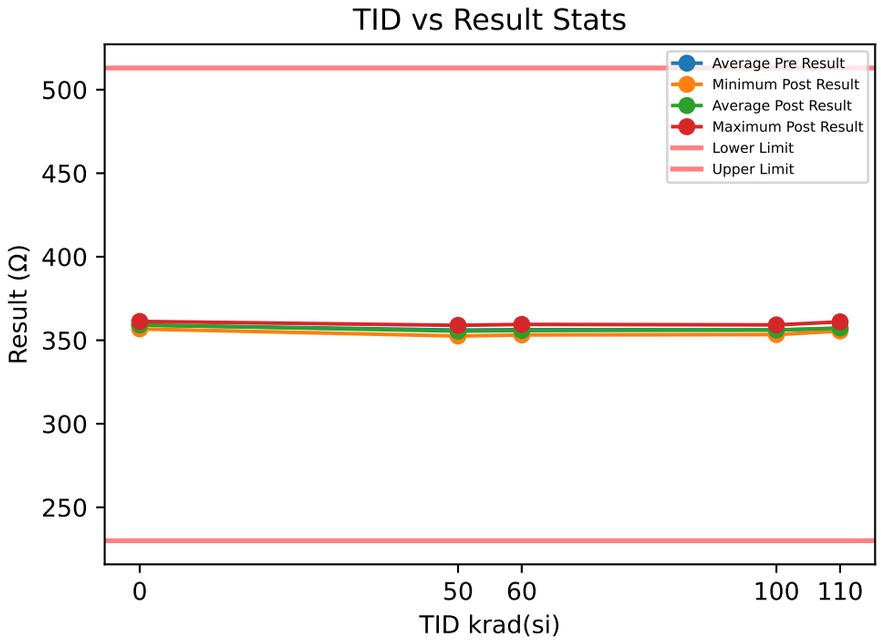
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

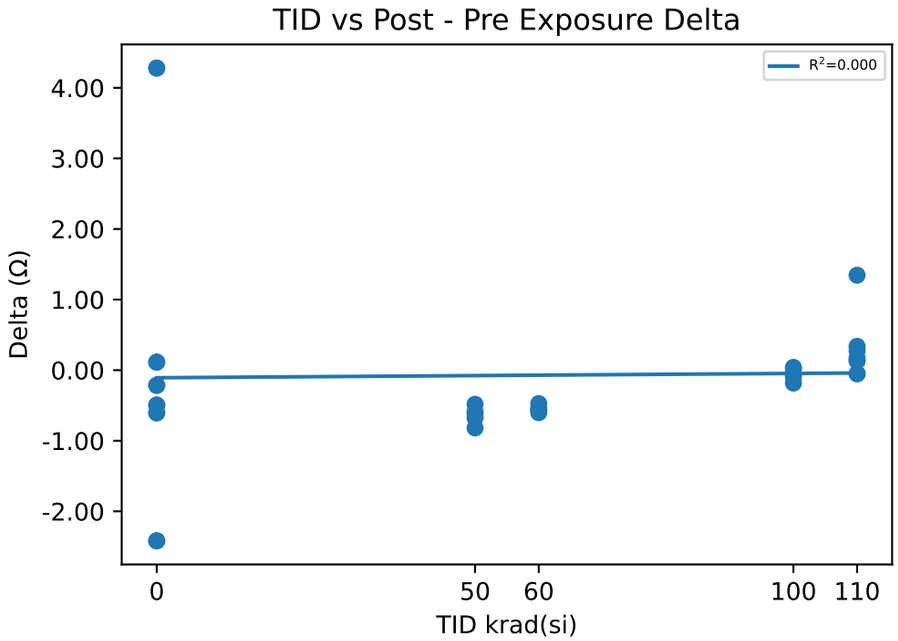
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.2873	2.2847	-0.0026
2	0	CU2	2.1161	2.115	-0.0011
3	0	CU3	2.2287	2.2251	-0.0036
11	50	Unbiased-50k	2.298	2.3041	0.0061
12	50	Unbiased-50k	2.3566	2.3584	0.0018
13	50	Unbiased-50k	2.2023	2.1999	-0.0024
14	50	Unbiased-50k	2.3539	2.3701	0.0162
16	50	Unbiased-50k	2.3264	2.3265	0.0001
17	60	Biased-50k	2.2972	2.3265	0.0293
18	60	Biased-50k	2.2849	2.3039	0.019
19	60	Biased-50k	2.2623	2.286	0.0237
20	60	Biased-50k	2.2942	2.3169	0.0227
21	60	Biased-50k	2.3057	2.3326	0.0269
24	100	Unbiased-100k	2.2618	2.2551	-0.0067
25	100	Unbiased-100k	2.131	2.1364	0.0054
26	100	Unbiased-100k	2.1258	2.1266	0.0008
27	100	Unbiased-100k	2.0896	2.0903	0.0007
28	100	Unbiased-100k	2.2548	2.2461	-0.0087
29	110	Biased-100k	2.2186	2.2721	0.0535
30	110	Biased-100k	2.3731	2.4272	0.0541
31	110	Biased-100k	2.2298	2.2815	0.0517
32	110	Biased-100k	2.2384	2.3645	0.1261
34	110	Biased-100k	2.1817	2.2347	0.053

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1161	2.2107	2.2873	0.087008	2.115	2.2083	2.2847	0.086093	-0.0036	-0.0024333	-0.0011	0.0012583
50	2.2023	2.3074	2.3566	0.0634	2.1999	2.3118	2.3701	0.067763	-0.0024	0.00436	0.0162	0.0073077
60	2.2623	2.2889	2.3057	0.016604	2.286	2.3132	2.3326	0.018663	0.019	0.02432	0.0293	0.0039613
100	2.0896	2.1726	2.2618	0.07988	2.0903	2.1709	2.2551	0.074823	-0.0087	-0.0017	0.0054	0.0058399
110	2.1817	2.2483	2.3731	0.073029	2.2347	2.316	2.4272	0.078174	0.0517	0.06768	0.1261	0.03267

Device Test: 40.5 R_SS_DISCHARGE(SoftStart|Resistance/SS1/3/3///90.9/634//0///@R_SS_DISCHARGE)





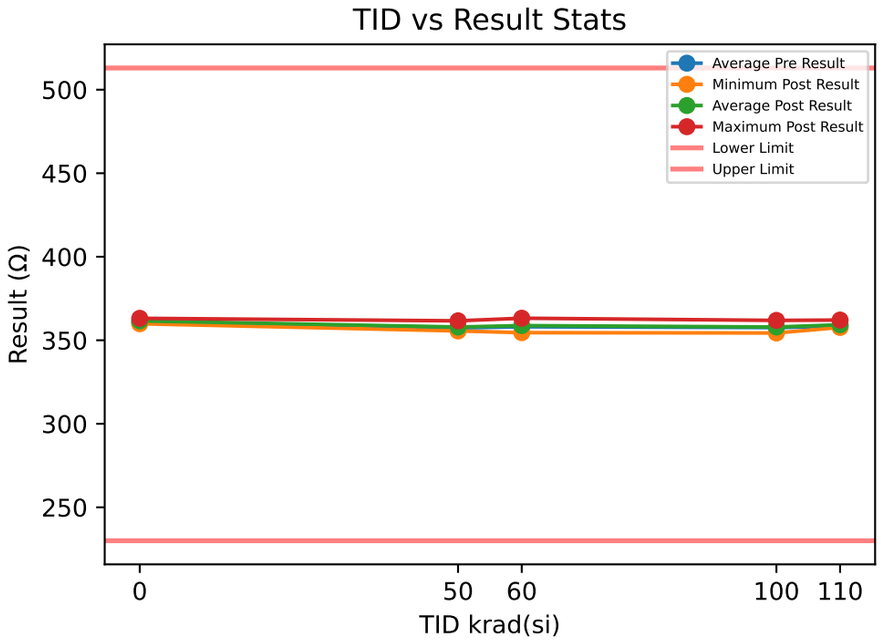
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

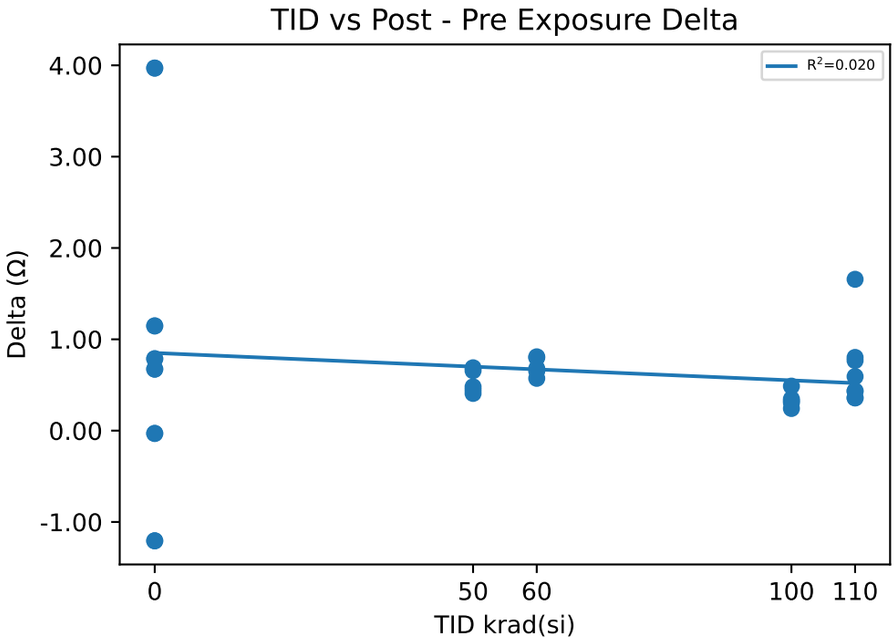
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	360.35	359.85	-0.4945
2	0	CU2	356.99	356.77	-0.2149
3	0	CU3	359.87	359.98	0.1134
11	50	Unbiased-50k	356.98	356.39	-0.588
12	50	Unbiased-50k	355.76	355.15	-0.6155
13	50	Unbiased-50k	353.35	352.53	-0.8183
14	50	Unbiased-50k	354.98	354.3	-0.6753
16	50	Unbiased-50k	359.4	358.92	-0.4829
17	60	Biased-50k	358.33	357.77	-0.5649
18	60	Biased-50k	353.79	353.18	-0.6026
19	60	Biased-50k	354.69	354.15	-0.5368
20	60	Biased-50k	354.98	354.42	-0.5626
21	60	Biased-50k	359.96	359.49	-0.4735
24	100	Unbiased-100k	357.54	357.58	0.0394
25	100	Unbiased-100k	353.45	353.39	-0.0643
26	100	Unbiased-100k	355.82	355.84	0.0202
27	100	Unbiased-100k	354.95	354.77	-0.1829
28	100	Unbiased-100k	359.29	359.19	-0.0943
29	110	Biased-100k	355.46	355.8	0.3378
30	110	Biased-100k	360.85	361.02	0.1728
31	110	Biased-100k	357.03	357.3	0.273
32	110	Biased-100k	354.18	355.53	1.3455
34	110	Biased-100k	357.21	357.16	-0.0501

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	356.99	359.07	360.35	1.8183	356.77	358.87	359.98	1.8175	-0.4945	-0.19867	0.1134	0.30427
50	353.35	356.1	359.4	2.2698	352.53	355.46	358.92	2.3896	-0.8183	-0.636	-0.4829	0.12343
60	353.79	356.35	359.96	2.6539	353.18	355.8	359.49	2.6896	-0.6026	-0.54808	-0.4735	0.047842
100	353.45	356.21	359.29	2.2683	353.39	356.15	359.19	2.2879	-0.1829	-0.05638	0.0394	0.090203
110	354.18	356.95	360.85	2.5074	355.53	357.36	361.02	2.1933	-0.0501	0.4158	1.3455	0.54012

Device Test: 40.6 R_SS_DISCHARGE(SoftStart|Resistance/SS2/3/3///90.9/634//0///@R_SS_DISCHARGE)





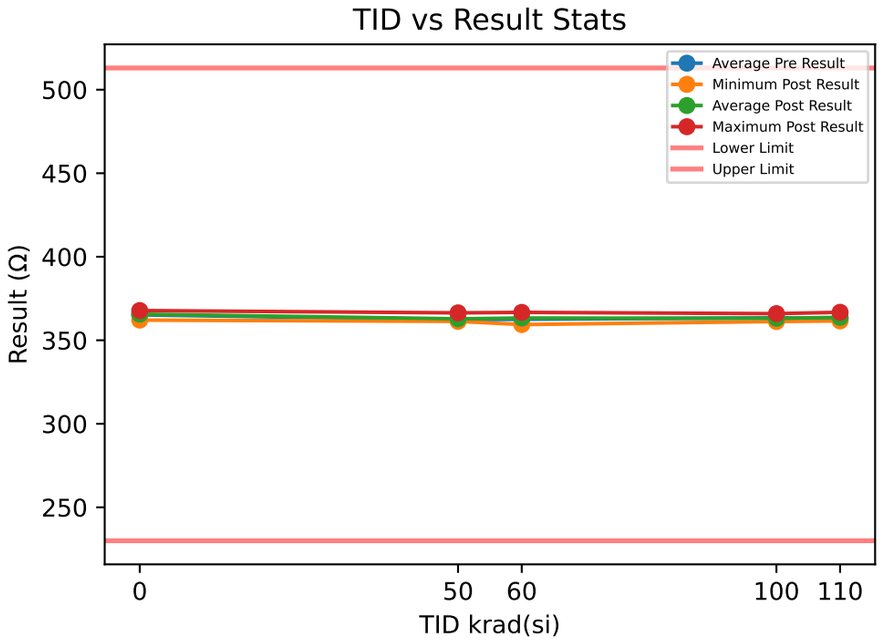
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

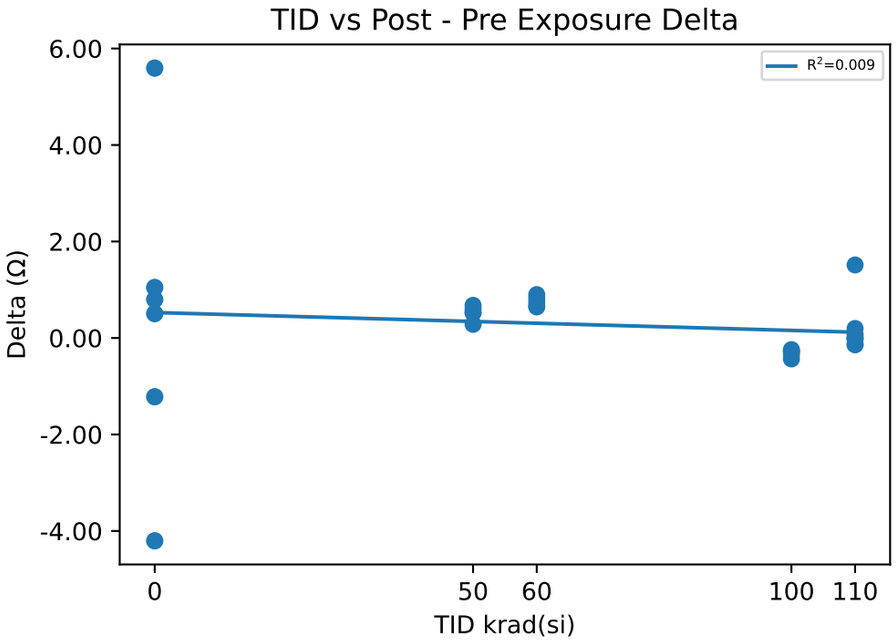
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	361.85	362.53	0.6736
2	0	CU2	359.17	359.96	0.7869
3	0	CU3	361.1	362.24	1.1467
11	50	Unbiased-50k	358.1	358.58	0.4797
12	50	Unbiased-50k	356.93	357.59	0.6566
13	50	Unbiased-50k	355.16	355.57	0.4075
14	50	Unbiased-50k	355.79	356.23	0.4448
16	50	Unbiased-50k	360.94	361.63	0.6882
17	60	Biased-50k	359.57	360.38	0.8083
18	60	Biased-50k	353.98	354.55	0.5727
19	60	Biased-50k	356.89	357.54	0.652
20	60	Biased-50k	357.54	358.22	0.6804
21	60	Biased-50k	362.4	363.2	0.7998
24	100	Unbiased-100k	358.99	359.47	0.4873
25	100	Unbiased-100k	354.01	354.36	0.3467
26	100	Unbiased-100k	357.01	357.32	0.306
27	100	Unbiased-100k	356.3	356.55	0.2424
28	100	Unbiased-100k	361.57	361.89	0.3251
29	110	Biased-100k	356.9	357.67	0.7675
30	110	Biased-100k	361.51	362.1	0.5924
31	110	Biased-100k	358.18	358.99	0.8016
32	110	Biased-100k	356.17	357.82	1.6572
34	110	Biased-100k	359	359.36	0.3587

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	359.17	360.71	361.85	1.3818	359.96	361.58	362.53	1.4073	0.6736	0.86907	1.1467	0.24702
50	355.16	357.38	360.94	2.284	355.57	357.92	361.63	2.3816	0.4075	0.53536	0.6882	0.12817
60	353.98	358.08	362.4	3.1399	354.55	358.78	363.2	3.2342	0.5727	0.70264	0.8083	0.10068
100	354.01	357.58	361.57	2.8536	354.36	357.92	361.89	2.8784	0.2424	0.3415	0.4873	0.090325
110	356.17	358.35	361.51	2.0786	357.67	359.19	362.1	1.7824	0.3587	0.83548	1.6572	0.49178

Device Test: 40.7 R_SS_DISCHARGE(SoftStart|Resistance/SS3/3/3///90.9/634//0///@R_SS_DISCHARGE)





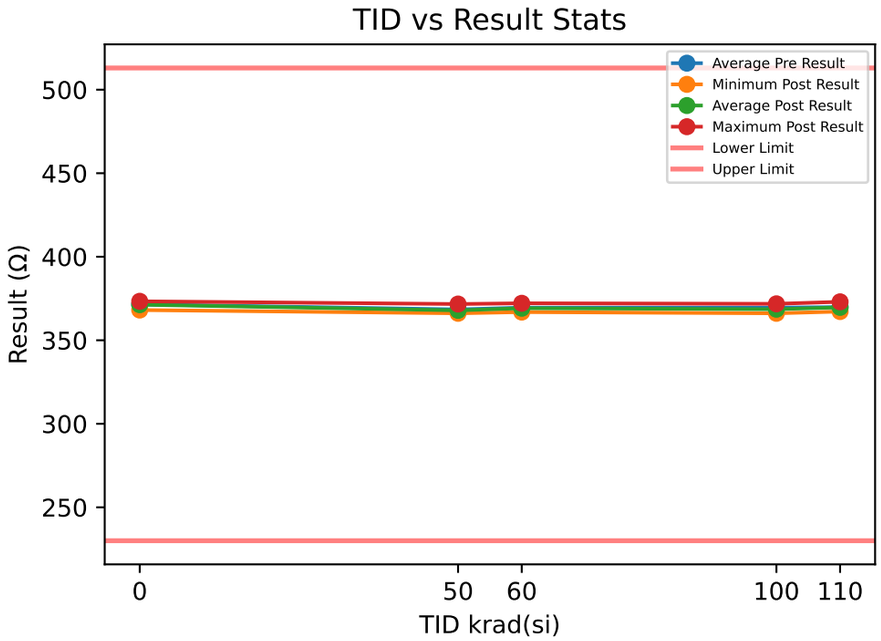
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

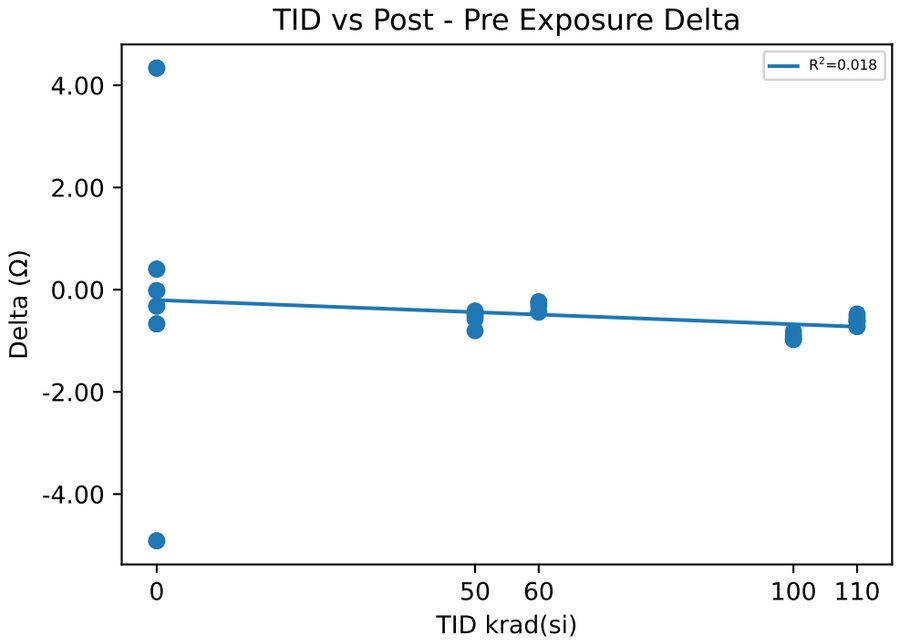
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	367.27	367.77	0.5051
2	0	CU2	362.04	362.84	0.7984
3	0	CU3	366.27	367.32	1.0468
11	50	Unbiased-50k	361.89	362.49	0.6004
12	50	Unbiased-50k	361.37	361.9	0.525
13	50	Unbiased-50k	361.02	361.31	0.2828
14	50	Unbiased-50k	361.57	362.09	0.5238
16	50	Unbiased-50k	365.72	366.4	0.677
17	60	Biased-50k	364.12	364.94	0.8227
18	60	Biased-50k	358.77	359.41	0.6438
19	60	Biased-50k	361.91	362.57	0.6613
20	60	Biased-50k	362.17	362.91	0.7393
21	60	Biased-50k	365.79	366.69	0.8994
24	100	Unbiased-100k	364.15	363.91	-0.241
25	100	Unbiased-100k	361.55	361.21	-0.3474
26	100	Unbiased-100k	362.18	361.91	-0.2647
27	100	Unbiased-100k	363.1	362.67	-0.4334
28	100	Unbiased-100k	366.22	365.93	-0.2923
29	110	Biased-100k	361.51	361.59	0.0725
30	110	Biased-100k	366.74	366.75	0.0091
31	110	Biased-100k	362.17	362.37	0.1975
32	110	Biased-100k	360.53	362.05	1.5138
34	110	Biased-100k	364.32	364.18	-0.1378

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	362.04	365.19	367.27	2.7762	362.84	365.98	367.77	2.7276	0.5051	0.78343	1.0468	0.27116
50	361.02	362.32	365.72	1.9306	361.31	362.84	366.4	2.0369	0.2828	0.5218	0.677	0.14782
60	358.77	362.55	365.79	2.6374	359.41	363.3	366.69	2.7382	0.6438	0.7533	0.8994	0.10818
100	361.55	363.44	366.22	1.8385	361.21	363.13	365.93	1.8609	-0.4334	-0.31576	-0.241	0.07679
110	360.53	363.06	366.74	2.484	361.59	363.39	366.75	2.1214	-0.1378	0.33102	1.5138	0.67213

Device Test: 40.8 R_SS_DISCHARGE(SoftStart|Resistance/SS4/3/3///90.9/634//0///@R_SS_DISCHARGE)





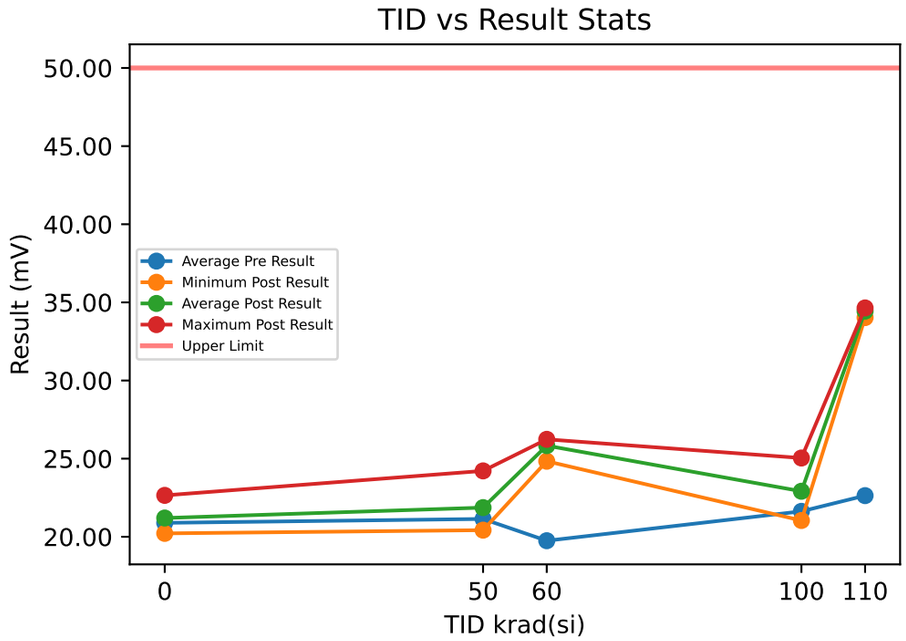
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

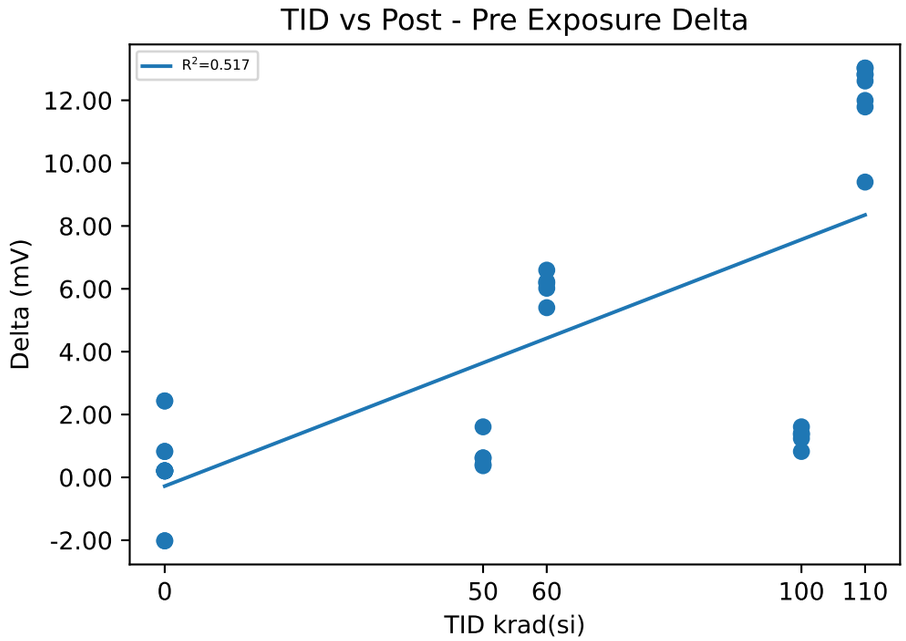
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	372.92	372.25	-0.6692
2	0	CU2	368.54	368.22	-0.3209
3	0	CU3	373.01	372.99	-0.0192
11	50	Unbiased-50k	367.72	367.14	-0.5759
12	50	Unbiased-50k	367.71	367.25	-0.4623
13	50	Unbiased-50k	366.94	366.14	-0.8031
14	50	Unbiased-50k	367.76	367.25	-0.51
16	50	Unbiased-50k	372.09	371.68	-0.4146
17	60	Biased-50k	370.54	370.31	-0.2332
18	60	Biased-50k	367.3	366.87	-0.4296
19	60	Biased-50k	368.34	368.08	-0.2529
20	60	Biased-50k	368.93	368.49	-0.4415
21	60	Biased-50k	372.44	372.13	-0.3126
24	100	Unbiased-100k	370.24	369.42	-0.817
25	100	Unbiased-100k	367.11	366.14	-0.9727
26	100	Unbiased-100k	367.58	366.69	-0.8886
27	100	Unbiased-100k	369.83	368.85	-0.9779
28	100	Unbiased-100k	372.74	371.81	-0.9262
29	110	Biased-100k	367.72	367.19	-0.5263
30	110	Biased-100k	373.62	373.01	-0.6094
31	110	Biased-100k	368.95	368.47	-0.475
32	110	Biased-100k	368.02	367.44	-0.5759
34	110	Biased-100k	371.02	370.3	-0.7213

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	368.54	371.49	373.01	2.5512	368.22	371.15	372.99	2.5641	-0.6692	-0.33643	-0.0192	0.32528
50	366.94	368.44	372.09	2.0688	366.14	367.89	371.68	2.1689	-0.8031	-0.55318	-0.4146	0.15191
60	367.3	369.51	372.44	2.0155	366.87	369.18	372.13	2.0602	-0.4415	-0.33396	-0.2332	0.097329
100	367.11	369.5	372.74	2.2652	366.14	368.58	371.81	2.2775	-0.9779	-0.91648	-0.817	0.066523
110	367.72	369.87	373.62	2.4651	367.19	369.29	373.01	2.4164	-0.7213	-0.58158	-0.475	0.093197

Device Test: 40.9 V_SS_START(SoftStart|MaxStartupVoltage/SS1/3/3///90.9/634//0///@V_SS_START)





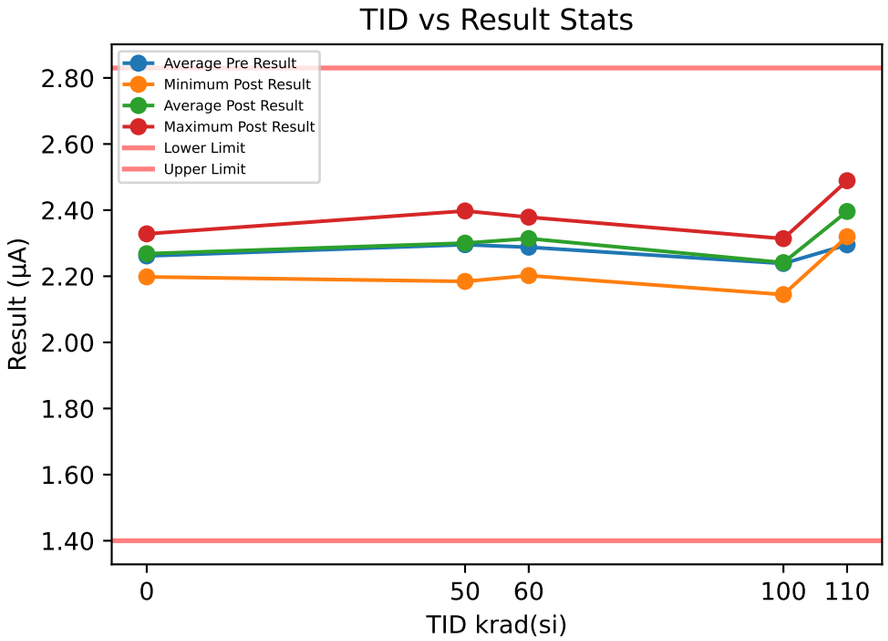
Test Results (Upper Limit = 50.0 (mV))

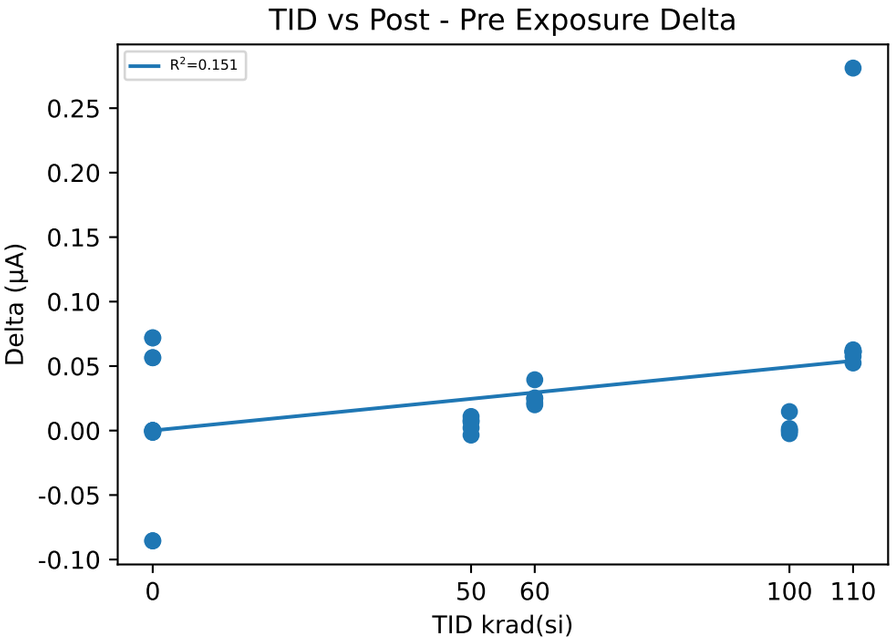
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	20.218	20.424	0.2061
2	0	CU2	22.444	22.65	0.2061
3	0	CU3	20.012	20.218	0.2061
11	50	Unbiased-50k	20.012	20.424	0.4122
12	50	Unbiased-50k	23.846	24.217	0.371
13	50	Unbiased-50k	20.012	20.631	0.6183
14	50	Unbiased-50k	18.817	20.424	1.6076
16	50	Unbiased-50k	23.021	23.64	0.6183
17	60	Biased-50k	20.012	26.03	6.018
18	60	Biased-50k	19.435	24.835	5.3998
19	60	Biased-50k	20.012	26.236	6.2241
20	60	Biased-50k	19.641	26.236	6.5951
21	60	Biased-50k	19.641	25.824	6.1829
24	100	Unbiased-100k	21.414	22.65	1.2366
25	100	Unbiased-100k	20.218	21.62	1.4014
26	100	Unbiased-100k	23.433	25.041	1.6076
27	100	Unbiased-100k	20.218	21.043	0.8244
28	100	Unbiased-100k	22.856	24.217	1.3603
29	110	Biased-100k	22.032	34.645	12.613
30	110	Biased-100k	22.65	34.645	11.995
31	110	Biased-100k	22.238	34.027	11.789
32	110	Biased-100k	24.629	34.027	9.3981
34	110	Biased-100k	21.62	34.439	12.819

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.012	20.892	22.444	1.3485	20.218	21.098	22.65	1.3485	0.2061	0.2061	0.2061	2.0532e-15
50	18.817	21.142	23.846	2.168	20.424	21.867	24.217	1.8943	0.371	0.72548	1.6076	0.50619
60	19.435	19.748	20.012	0.25511	24.835	25.832	26.236	0.5832	5.3998	6.084	6.5951	0.43678
100	20.218	21.628	23.433	1.4823	21.043	22.914	25.041	1.6932	0.8244	1.2861	1.6076	0.29059
110	21.62	22.634	24.629	1.1755	34.027	34.357	34.645	0.31257	9.3981	11.723	12.819	1.3673

Device Test: 41.1 I_SS(SoftStart|ChargeCurrent/SS1/7/7///90.9/634//0///@I_SS)





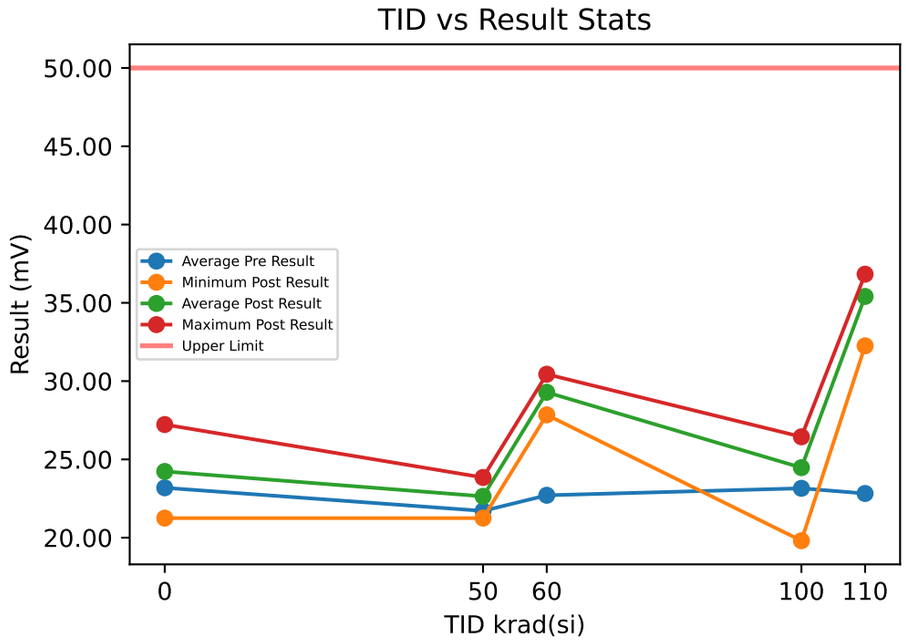
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

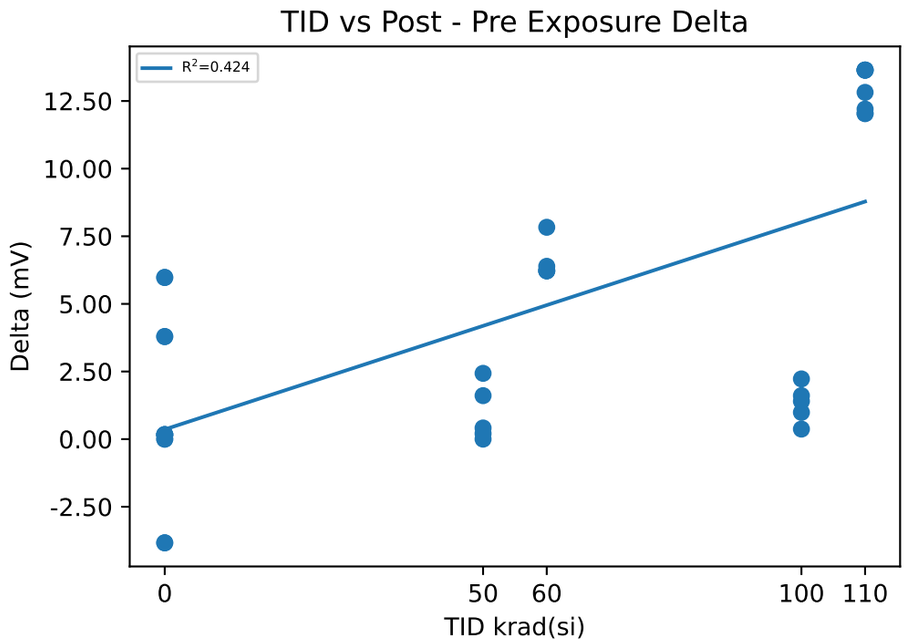
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3282	2.3282	0
2	0	CU2	2.2564	2.2564	0
3	0	CU3	2.1994	2.1981	-0.0013
11	50	Unbiased-50k	2.1777	2.1844	0.0067
12	50	Unbiased-50k	2.3797	2.3762	-0.0035
13	50	Unbiased-50k	2.2763	2.2784	0.0021
14	50	Unbiased-50k	2.3866	2.3975	0.0109
16	50	Unbiased-50k	2.2569	2.2649	0.008
17	60	Biased-50k	2.328	2.3533	0.0253
18	60	Biased-50k	2.3124	2.334	0.0216
19	60	Biased-50k	2.2775	2.3021	0.0246
20	60	Biased-50k	2.3393	2.3787	0.0394
21	60	Biased-50k	2.182	2.202	0.02
24	100	Unbiased-100k	2.299	2.2966	-0.0024
25	100	Unbiased-100k	2.2991	2.3138	0.0147
26	100	Unbiased-100k	2.1646	2.1662	0.0016
27	100	Unbiased-100k	2.145	2.1445	-0.0005
28	100	Unbiased-100k	2.2851	2.2853	0.0002
29	110	Biased-100k	2.2673	2.3197	0.0524
30	110	Biased-100k	2.3274	2.39	0.0626
31	110	Biased-100k	2.3407	2.3983	0.0576
32	110	Biased-100k	2.2079	2.489	0.2811
34	110	Biased-100k	2.3315	2.3924	0.0609

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1994	2.2613	2.3282	0.064542	2.1981	2.2609	2.3282	0.065167	-0.0013	-0.00043333	0	0.00075056
50	2.1777	2.2954	2.3866	0.08821	2.1844	2.3003	2.3975	0.087141	-0.0035	0.00484	0.0109	0.0056399
60	2.182	2.2878	2.3393	0.063587	2.202	2.314	2.3787	0.068586	0.02	0.02618	0.0394	0.0077008
100	2.145	2.2386	2.2991	0.076986	2.1445	2.2413	2.3138	0.079468	-0.0024	0.00272	0.0147	0.0068503
110	2.2079	2.295	2.3407	0.056622	2.3197	2.3979	2.489	0.060223	0.0524	0.10292	0.2811	0.099682

Device Test: 41.10 V_SS_START(SoftStart|MaxStartupVoltage/SS2/7/7///90.9/634//0///@V_SS_START)





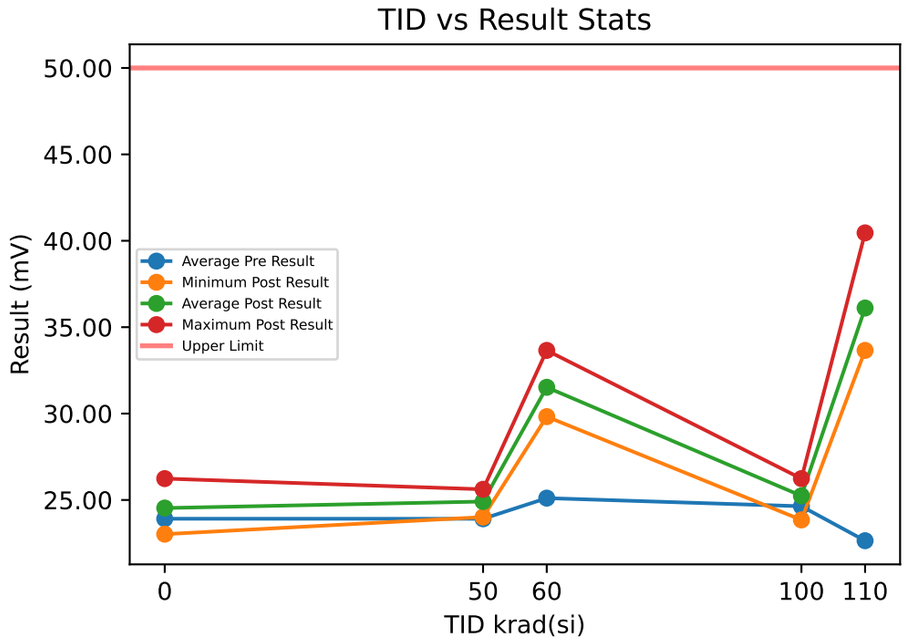
Test Results (Upper Limit = 50.0 (mV))

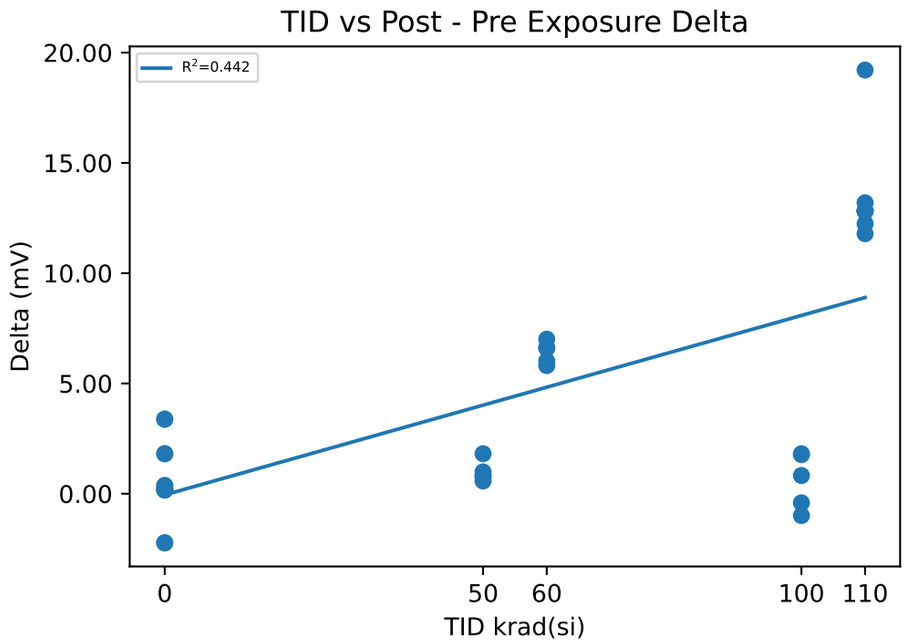
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	21.249	21.249	0
2	0	CU2	27.061	27.226	0.1649
3	0	CU3	21.249	21.414	0.1648
11	50	Unbiased-50k	23.021	23.021	0
12	50	Unbiased-50k	20.837	22.444	1.6075
13	50	Unbiased-50k	22.444	22.65	0.2061
14	50	Unbiased-50k	21.414	23.846	2.432
16	50	Unbiased-50k	20.837	21.249	0.4122
17	60	Biased-50k	24.217	30.441	6.2242
18	60	Biased-50k	23.227	29.451	6.2242
19	60	Biased-50k	21.62	27.844	6.2242
20	60	Biased-50k	21.62	29.451	7.8318
21	60	Biased-50k	22.856	29.245	6.3891
24	100	Unbiased-100k	23.64	25.247	1.6076
25	100	Unbiased-100k	23.64	24.629	0.9893
26	100	Unbiased-100k	24.835	26.236	1.4014
27	100	Unbiased-100k	24.217	26.442	2.2258
28	100	Unbiased-100k	19.435	19.806	0.371
29	110	Biased-100k	24.629	36.83	12.201
30	110	Biased-100k	24.011	36.83	12.819
31	110	Biased-100k	20.218	32.254	12.036
32	110	Biased-100k	23.433	35.47	12.036
34	110	Biased-100k	21.826	35.47	13.644

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.249	23.186	27.061	3.3555	21.249	23.296	27.226	3.4041	0	0.1099	0.1649	0.095176
50	20.837	21.71	23.021	0.98383	21.249	22.642	23.846	0.94508	0	0.93156	2.432	1.0455
60	21.62	22.708	24.217	1.1109	27.844	29.287	30.441	0.93135	6.2242	6.5787	7.8318	0.70413
100	19.435	23.153	24.835	2.1364	19.806	24.472	26.442	2.7107	0.371	1.319	2.2258	0.69278
110	20.218	22.823	24.629	1.7904	32.254	35.371	36.83	1.8701	12.036	12.547	13.644	0.6926

Device Test: 41.11 V_SS_START(SoftStart|MaxStartupVoltage/SS3/7/7///90.9/634//0///@V_SS_START)





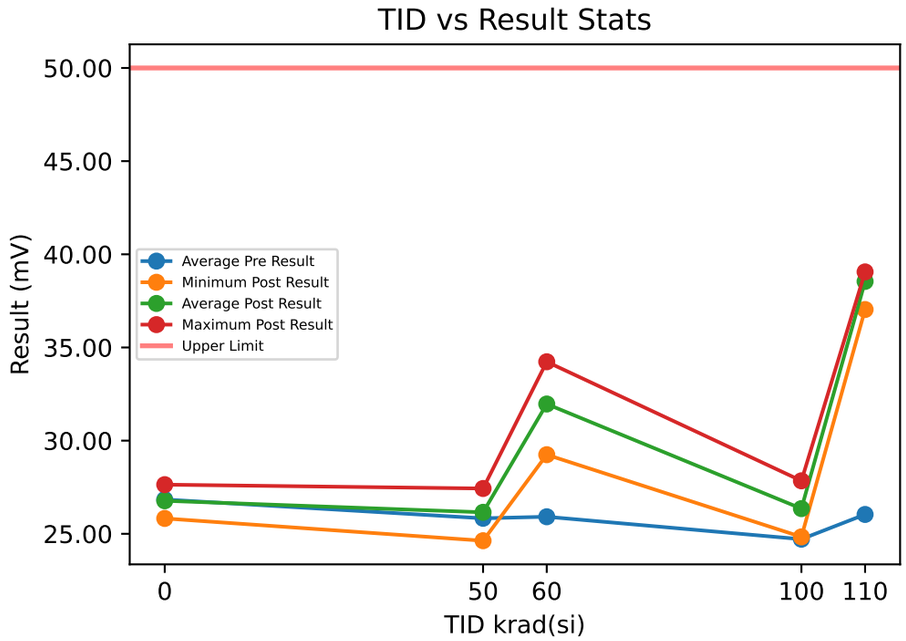
Test Results (Upper Limit = 50.0 (mV))

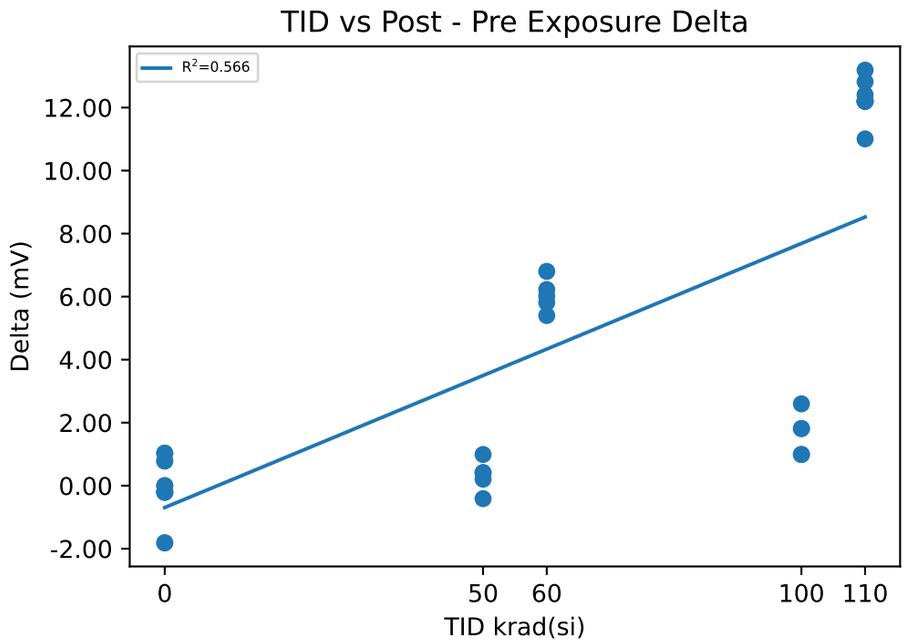
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	25.247	25.453	0.2061
2	0	CU2	23.64	24.011	0.371
3	0	CU3	22.856	23.021	0.1649
11	50	Unbiased-50k	24.835	25.618	0.7831
12	50	Unbiased-50k	23.846	24.835	0.9893
13	50	Unbiased-50k	24.423	25.247	0.8244
14	50	Unbiased-50k	23.433	24.011	0.5771
16	50	Unbiased-50k	23.021	24.835	1.8137
17	60	Biased-50k	24.011	30.647	6.6364
18	60	Biased-50k	24.629	30.647	6.0181
19	60	Biased-50k	24.011	29.823	5.812
20	60	Biased-50k	25.824	32.831	7.0074
21	60	Biased-50k	27.061	33.656	6.5952
24	100	Unbiased-100k	23.021	23.846	0.8244
25	100	Unbiased-100k	25.453	25.041	-0.4122
26	100	Unbiased-100k	26.442	25.453	-0.9892
27	100	Unbiased-100k	24.423	26.236	1.8136
28	100	Unbiased-100k	23.846	25.618	1.7724
29	110	Biased-100k	21.414	33.656	12.242
30	110	Biased-100k	25.041	38.231	13.19
31	110	Biased-100k	22.856	34.645	11.789
32	110	Biased-100k	21.249	40.457	19.208
34	110	Biased-100k	22.65	35.47	12.819

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.856	23.914	25.247	1.2189	23.021	24.162	25.453	1.223	0.1649	0.24733	0.371	0.10906
50	23.021	23.912	24.835	0.73136	24.011	24.909	25.618	0.59902	0.5771	0.99752	1.8137	0.4793
60	24.011	25.107	27.061	1.3195	29.823	31.521	33.656	1.6346	5.812	6.4138	7.0074	0.48825
100	23.021	24.637	26.442	1.3425	23.846	25.239	26.236	0.88951	-0.9892	0.6018	1.8136	1.2696
110	21.249	22.642	25.041	1.5208	33.656	36.492	40.457	2.7949	11.789	13.85	19.208	3.0431

Device Test: 41.12 V_SS_START(SoftStart|MaxStartupVoltage/SS4/7/7///90.9/634//0///@V_SS_START)





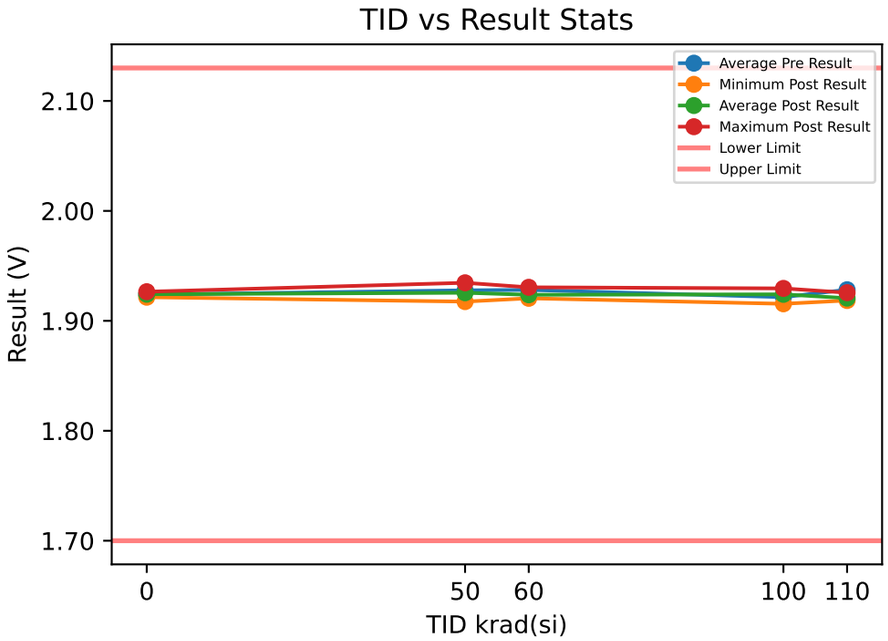
Test Results (Upper Limit = 50.0 (mV))

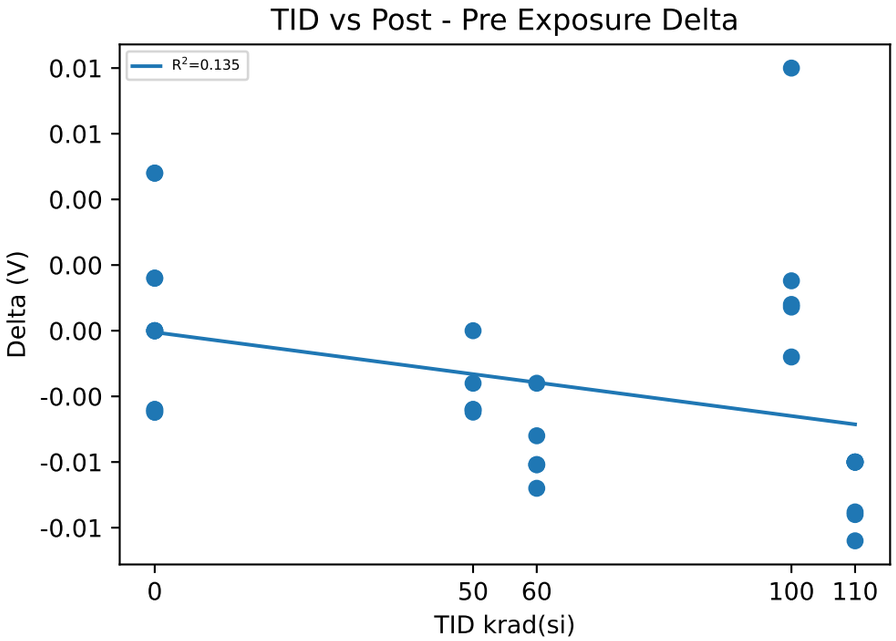
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	26.855	26.648	-0.2061
2	0	CU2	26.03	25.824	-0.2061
3	0	CU3	27.638	27.638	0
11	50	Unbiased-50k	24.423	24.629	0.2061
12	50	Unbiased-50k	26.442	27.432	0.9893
13	50	Unbiased-50k	26.236	26.648	0.4122
14	50	Unbiased-50k	26.236	25.824	-0.4122
16	50	Unbiased-50k	25.824	26.236	0.4122
17	60	Biased-50k	27.638	33.45	5.812
18	60	Biased-50k	23.846	29.245	5.3998
19	60	Biased-50k	27.432	34.233	6.8013
20	60	Biased-50k	25.824	31.842	6.0181
21	60	Biased-50k	24.835	31.059	6.2241
24	100	Unbiased-100k	23.846	24.835	0.9893
25	100	Unbiased-100k	26.442	27.432	0.9893
26	100	Unbiased-100k	26.03	27.844	1.8137
27	100	Unbiased-100k	23.021	25.618	2.5968
28	100	Unbiased-100k	24.217	26.03	1.8136
29	110	Biased-100k	26.03	38.437	12.407
30	110	Biased-100k	26.236	39.056	12.819
31	110	Biased-100k	25.247	38.437	13.19
32	110	Biased-100k	26.03	37.036	11.006
34	110	Biased-100k	26.648	38.85	12.201

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.03	26.841	27.638	0.80389	25.824	26.703	27.638	0.9081	-0.2061	-0.1374	0	0.11899
50	24.423	25.832	26.442	0.8194	24.629	26.154	27.432	1.0391	-0.4122	0.32152	0.9893	0.5035
60	23.846	25.915	27.638	1.6375	29.245	31.966	34.233	1.9736	5.3998	6.0511	6.8013	0.51845
100	23.021	24.711	26.442	1.4652	24.835	26.352	27.844	1.2585	0.9893	1.6405	2.5968	0.67502
110	25.247	26.038	26.648	0.50933	37.036	38.363	39.056	0.78881	11.006	12.325	13.19	0.83004

Device Test: 41.13 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP1/7/7///90.9/634//0///@COMP_V_CLAMP)





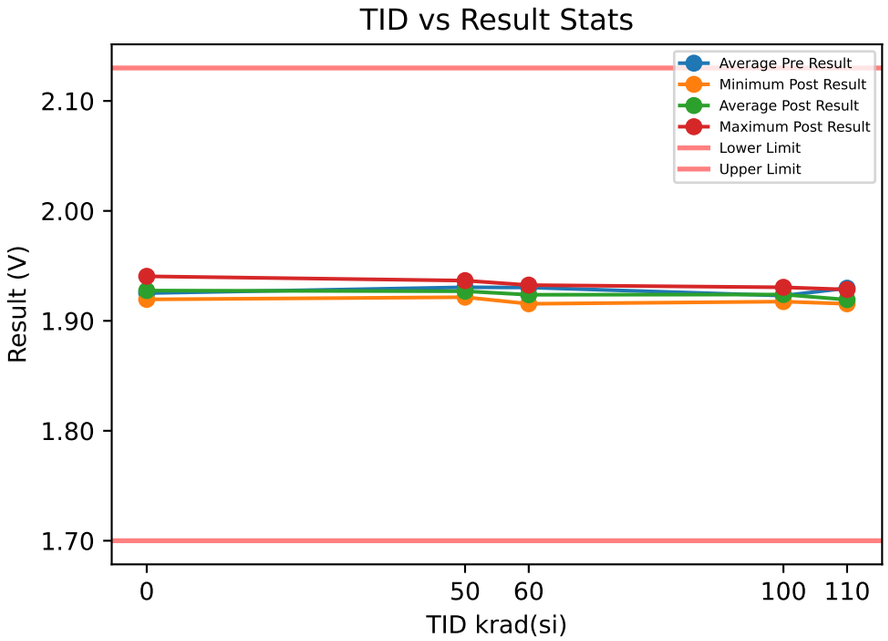
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

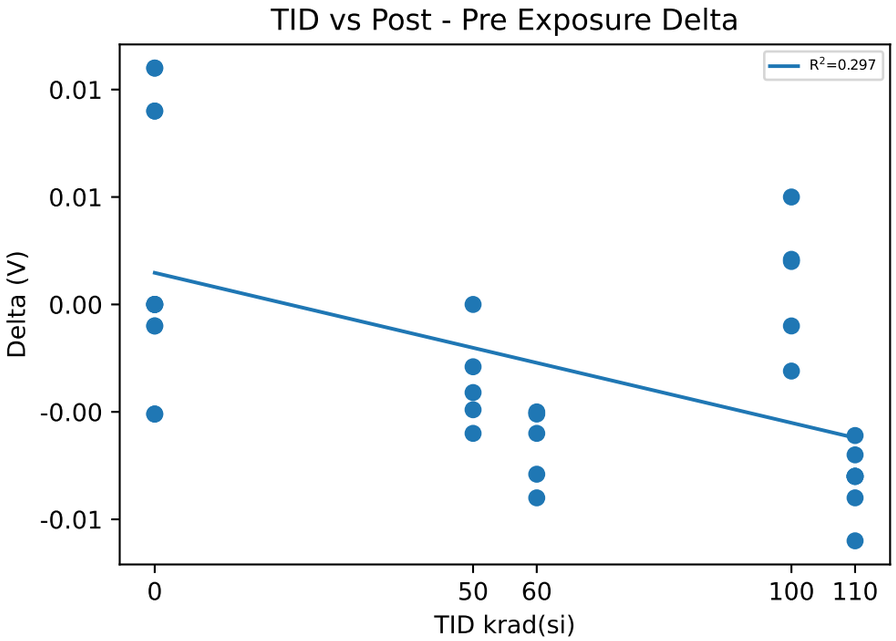
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9265	1.9265	0
2	0	CU2	1.9205	1.9225	0.002
3	0	CU3	1.9246	1.9246	0
11	50	Unbiased-50k	1.9205	1.9175	-0.003
12	50	Unbiased-50k	1.9346	1.9315	-0.0031
13	50	Unbiased-50k	1.9376	1.9346	-0.003
14	50	Unbiased-50k	1.9246	1.9246	0
16	50	Unbiased-50k	1.9215	1.9195	-0.002
17	60	Biased-50k	1.9275	1.9235	-0.004
18	60	Biased-50k	1.9356	1.9305	-0.0051
19	60	Biased-50k	1.9256	1.9205	-0.0051
20	60	Biased-50k	1.9285	1.9225	-0.006
21	60	Biased-50k	1.9235	1.9215	-0.002
24	100	Unbiased-100k	1.9246	1.9265	0.0019
25	100	Unbiased-100k	1.9285	1.9295	0.001
26	100	Unbiased-100k	1.9215	1.9205	-0.001
27	100	Unbiased-100k	1.9146	1.9155	0.0009
28	100	Unbiased-100k	1.9185	1.9285	0.01
29	110	Biased-100k	1.9275	1.9205	-0.007
30	110	Biased-100k	1.9325	1.9256	-0.0069
31	110	Biased-100k	1.9305	1.9225	-0.008
32	110	Biased-100k	1.9275	1.9225	-0.005
34	110	Biased-100k	1.9235	1.9185	-0.005

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9205	1.9239	1.9265	0.0030665	1.9225	1.9245	1.9265	0.0020008	0	0.00066667	0.002	0.0011547
50	1.9205	1.9278	1.9376	0.0078341	1.9175	1.9255	1.9346	0.0074097	-0.0031	-0.00222	0	0.0013198
60	1.9235	1.9281	1.9356	0.0045873	1.9205	1.9237	1.9305	0.0039623	-0.006	-0.00444	-0.002	0.0015372
100	1.9146	1.9215	1.9285	0.0053668	1.9155	1.9241	1.9295	0.0059414	-0.001	0.00256	0.01	0.004291
110	1.9235	1.9283	1.9325	0.0034205	1.9185	1.9219	1.9256	0.0026423	-0.008	-0.00638	-0.005	0.0013312

Device Test: 41.14 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP2/7/7///90.9/634//0///@COMP_V_CLAMP)





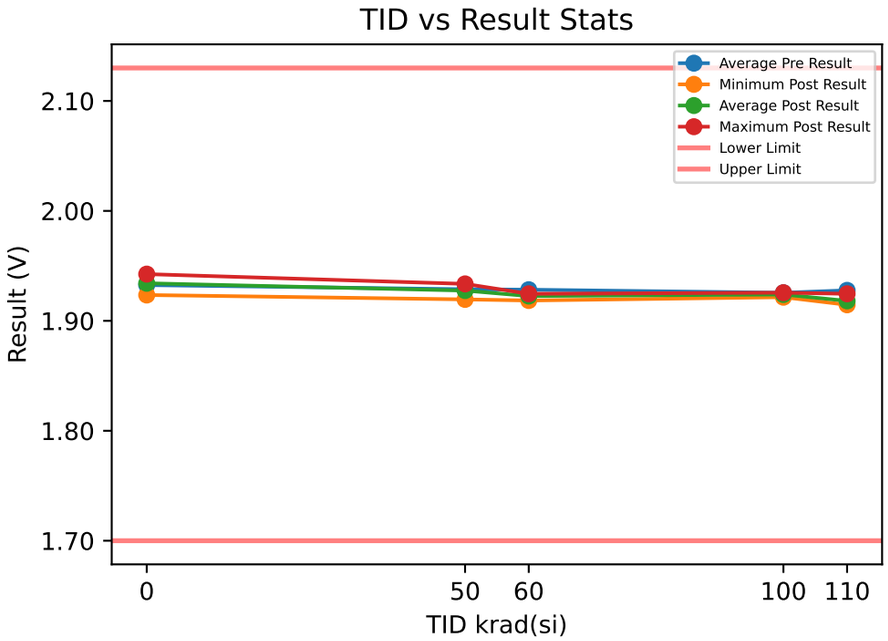
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

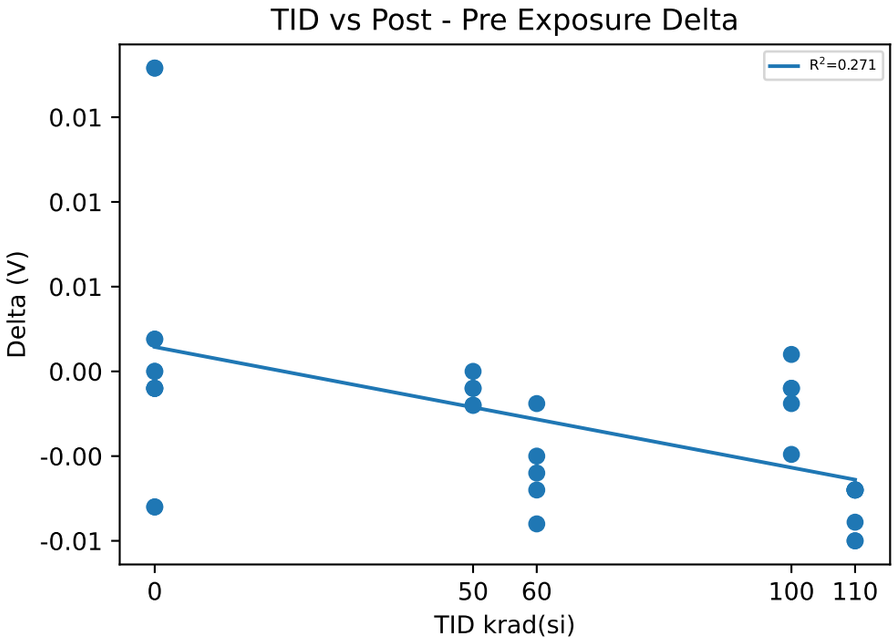
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9295	1.9295	0
2	0	CU2	1.9205	1.9195	-0.001
3	0	CU3	1.9256	1.9256	0
11	50	Unbiased-50k	1.9225	1.9225	0
12	50	Unbiased-50k	1.9336	1.9295	-0.0041
13	50	Unbiased-50k	1.9415	1.9366	-0.0049
14	50	Unbiased-50k	1.9275	1.9246	-0.0029
16	50	Unbiased-50k	1.9275	1.9215	-0.006
17	60	Biased-50k	1.9325	1.9246	-0.0079
18	60	Biased-50k	1.9376	1.9325	-0.0051
19	60	Biased-50k	1.9275	1.9225	-0.005
20	60	Biased-50k	1.9325	1.9235	-0.009
21	60	Biased-50k	1.9215	1.9155	-0.006
24	100	Unbiased-100k	1.9235	1.9256	0.0021
25	100	Unbiased-100k	1.9336	1.9305	-0.0031
26	100	Unbiased-100k	1.9235	1.9285	0.005
27	100	Unbiased-100k	1.9155	1.9175	0.002
28	100	Unbiased-100k	1.9185	1.9175	-0.001
29	110	Biased-100k	1.9285	1.9215	-0.007
30	110	Biased-100k	1.9346	1.9285	-0.0061
31	110	Biased-100k	1.9325	1.9235	-0.009
32	110	Biased-100k	1.9295	1.9185	-0.011
34	110	Biased-100k	1.9235	1.9155	-0.008

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9205	1.9252	1.9295	0.0045133	1.9195	1.9249	1.9295	0.0050402	-0.001	-0.00033333	0	0.00057735
50	1.9225	1.9305	1.9415	0.0072905	1.9215	1.9269	1.9366	0.006218	-0.006	-0.00358	0	0.0022993
60	1.9215	1.9303	1.9376	0.0060879	1.9155	1.9237	1.9325	0.0060615	-0.009	-0.0066	-0.005	0.0017762
100	1.9155	1.9229	1.9336	0.0068798	1.9175	1.9239	1.9305	0.0061141	-0.0031	0.001	0.005	0.0031233
110	1.9235	1.9297	1.9346	0.0042358	1.9155	1.9215	1.9285	0.0049497	-0.011	-0.00822	-0.0061	0.0018953

Device Test: 41.15 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP3/7/7///90.9/634//0///@COMP_V_CLAMP)





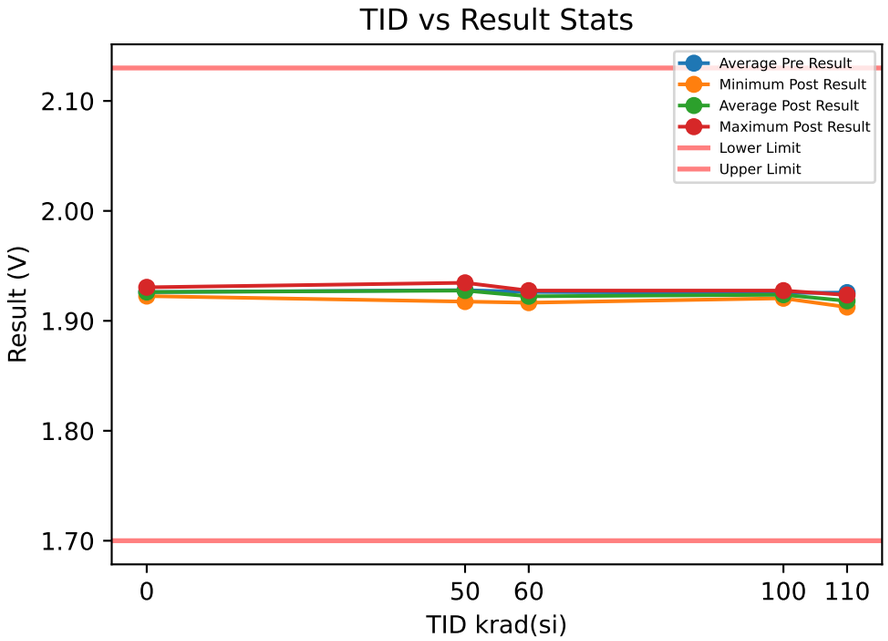
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

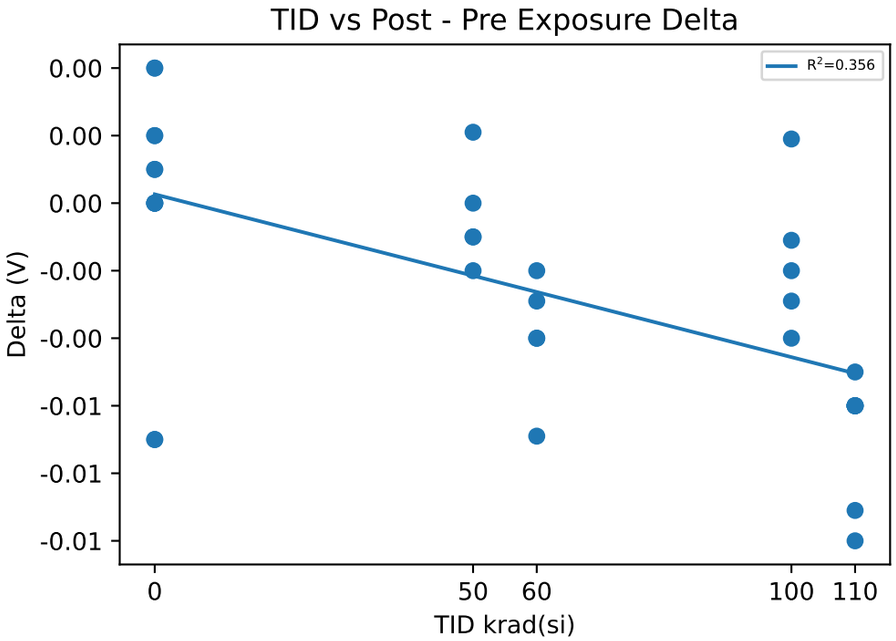
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9415	1.9415	0
2	0	CU2	1.9246	1.9265	0.0019
3	0	CU3	1.9315	1.9305	-0.001
11	50	Unbiased-50k	1.9305	1.9285	-0.002
12	50	Unbiased-50k	1.9285	1.9275	-0.001
13	50	Unbiased-50k	1.9305	1.9285	-0.002
14	50	Unbiased-50k	1.9336	1.9336	0
16	50	Unbiased-50k	1.9205	1.9195	-0.001
17	60	Biased-50k	1.9235	1.9185	-0.005
18	60	Biased-50k	1.9275	1.9215	-0.006
19	60	Biased-50k	1.9305	1.9235	-0.007
20	60	Biased-50k	1.9336	1.9246	-0.009
21	60	Biased-50k	1.9265	1.9246	-0.0019
24	100	Unbiased-100k	1.9235	1.9225	-0.001
25	100	Unbiased-100k	1.9295	1.9246	-0.0049
26	100	Unbiased-100k	1.9275	1.9256	-0.0019
27	100	Unbiased-100k	1.9225	1.9215	-0.001
28	100	Unbiased-100k	1.9246	1.9256	0.001
29	110	Biased-100k	1.9275	1.9175	-0.01
30	110	Biased-100k	1.9346	1.9246	-0.01
31	110	Biased-100k	1.9235	1.9146	-0.0089
32	110	Biased-100k	1.9295	1.9225	-0.007
34	110	Biased-100k	1.9235	1.9165	-0.007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9246	1.9325	1.9415	0.0084973	1.9265	1.9328	1.9415	0.0077675	-0.001	0.0003	0.0019	0.0014731
50	1.9205	1.9287	1.9336	0.0049439	1.9195	1.9275	1.9336	0.0050796	-0.002	-0.0012	0	0.00083666
60	1.9235	1.9283	1.9336	0.0038681	1.9185	1.9225	1.9246	0.002589	-0.009	-0.00578	-0.0019	0.0026253
100	1.9225	1.9255	1.9295	0.0029072	1.9215	1.924	1.9256	0.001869	-0.0049	-0.00156	0.001	0.0021478
110	1.9235	1.9277	1.9346	0.0046413	1.9146	1.9191	1.9246	0.0042241	-0.01	-0.00858	-0.007	0.0015106

Device Test: 41.16 COMP_V_CLAMP(SoftStart|ClampVoltage/COMP4/7/7///90.9/634//0///@COMP_V_CLAMP)





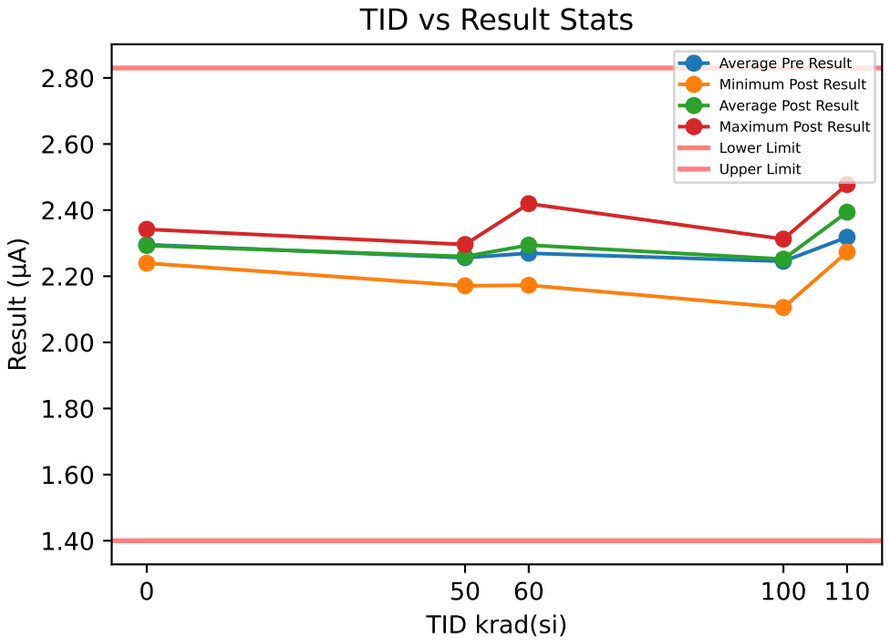
Test Results (Lower Limit = 1.7, Upper Limit = 2.13 (V))

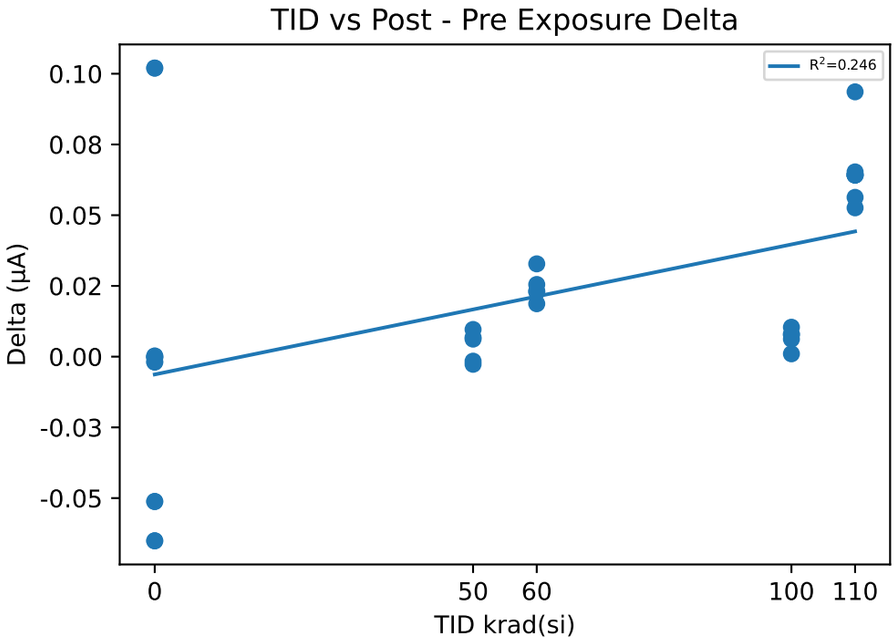
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.9265	1.9265	0
2	0	CU2	1.9225	1.9225	0
3	0	CU3	1.9295	1.9305	0.001
11	50	Unbiased-50k	1.9295	1.9275	-0.002
12	50	Unbiased-50k	1.9305	1.9295	-0.001
13	50	Unbiased-50k	1.9295	1.9285	-0.001
14	50	Unbiased-50k	1.9325	1.9346	0.0021
16	50	Unbiased-50k	1.9175	1.9175	0
17	60	Biased-50k	1.9225	1.9185	-0.004
18	60	Biased-50k	1.9295	1.9275	-0.002
19	60	Biased-50k	1.9205	1.9165	-0.004
20	60	Biased-50k	1.9315	1.9246	-0.0069
21	60	Biased-50k	1.9275	1.9246	-0.0029
24	100	Unbiased-100k	1.9265	1.9225	-0.004
25	100	Unbiased-100k	1.9246	1.9235	-0.0011
26	100	Unbiased-100k	1.9275	1.9246	-0.0029
27	100	Unbiased-100k	1.9225	1.9205	-0.002
28	100	Unbiased-100k	1.9256	1.9275	0.0019
29	110	Biased-100k	1.9256	1.9165	-0.0091
30	110	Biased-100k	1.9285	1.9235	-0.005
31	110	Biased-100k	1.9225	1.9125	-0.01
32	110	Biased-100k	1.9285	1.9225	-0.006
34	110	Biased-100k	1.9235	1.9175	-0.006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9225	1.9262	1.9295	0.0035119	1.9225	1.9265	1.9305	0.004	0	0.00033333	0.001	0.00057735
50	1.9175	1.9279	1.9325	0.0059414	1.9175	1.9275	1.9346	0.0062331	-0.002	-0.00038	0.0021	0.0015563
60	1.9205	1.9263	1.9315	0.0046583	1.9165	1.9223	1.9275	0.0046285	-0.0069	-0.00396	-0.002	0.0018447
100	1.9225	1.9253	1.9275	0.0019165	1.9205	1.9237	1.9275	0.0025965	-0.004	-0.00162	0.0019	0.0022421
110	1.9225	1.9257	1.9285	0.0027734	1.9125	1.9185	1.9235	0.0045277	-0.01	-0.00722	-0.005	0.0021891

Device Test: 41.2 I_SS(SoftStart|ChargeCurrent/SS2/7/7///90.9/634//0///@I_SS)





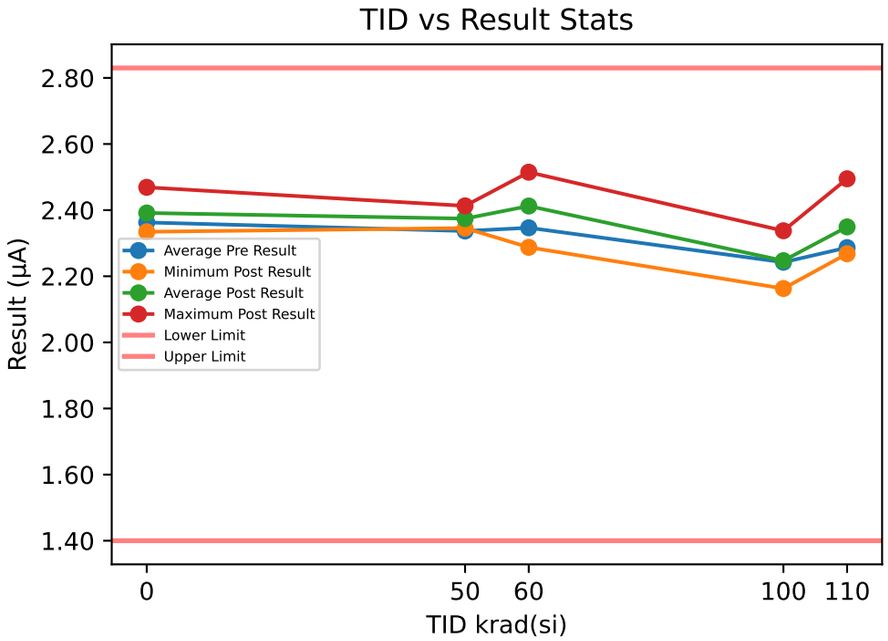
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

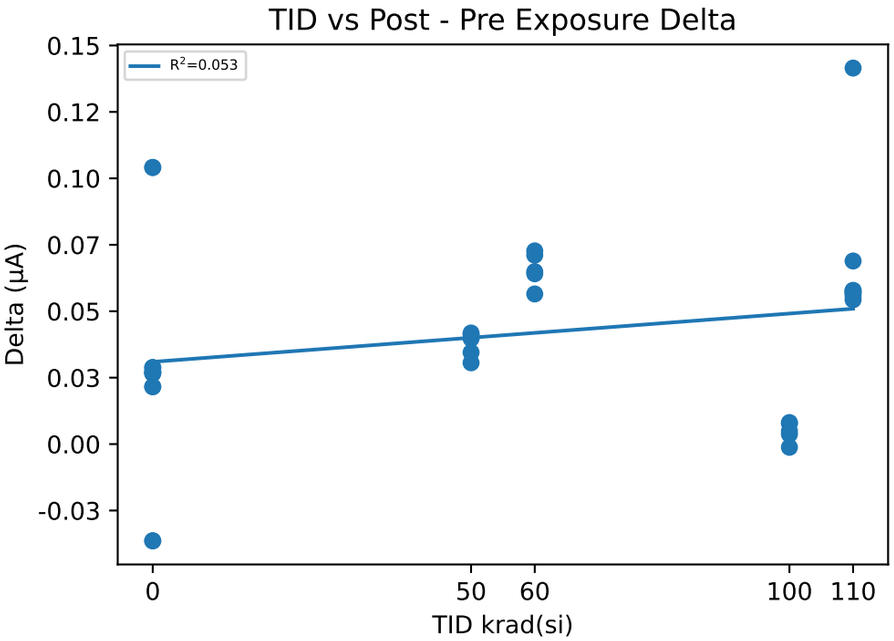
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3423	2.342	-0.0003
2	0	CU2	2.2398	2.24	0.0002
3	0	CU3	2.3047	2.3028	-0.0019
11	50	Unbiased-50k	2.2756	2.2824	0.0068
12	50	Unbiased-50k	2.1739	2.1712	-0.0027
13	50	Unbiased-50k	2.2898	2.296	0.0062
14	50	Unbiased-50k	2.2743	2.2839	0.0096
16	50	Unbiased-50k	2.2668	2.2652	-0.0016
17	60	Biased-50k	2.2419	2.2747	0.0328
18	60	Biased-50k	2.2377	2.2609	0.0232
19	60	Biased-50k	2.394	2.4195	0.0255
20	60	Biased-50k	2.3247	2.3434	0.0187
21	60	Biased-50k	2.1499	2.1728	0.0229
24	100	Unbiased-100k	2.2498	2.2508	0.001
25	100	Unbiased-100k	2.2813	2.2892	0.0079
26	100	Unbiased-100k	2.3063	2.3125	0.0062
27	100	Unbiased-100k	2.0974	2.1052	0.0078
28	100	Unbiased-100k	2.2914	2.3018	0.0104
29	110	Biased-100k	2.2206	2.2732	0.0526
30	110	Biased-100k	2.421	2.4773	0.0563
31	110	Biased-100k	2.3148	2.3801	0.0653
32	110	Biased-100k	2.2883	2.3819	0.0936
34	110	Biased-100k	2.3455	2.4097	0.0642

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2398	2.2956	2.3423	0.051852	2.24	2.2949	2.342	0.051453	-0.0019	-0.00066667	0.0002	0.001097
50	2.1739	2.2561	2.2898	0.046686	2.1712	2.2597	2.296	0.050698	-0.0027	0.00366	0.0096	0.0054706
60	2.1499	2.2696	2.394	0.093038	2.1728	2.2943	2.4195	0.092666	0.0187	0.02462	0.0328	0.0051891
100	2.0974	2.2452	2.3063	0.085201	2.1052	2.2519	2.3125	0.085258	0.001	0.00666	0.0104	0.0035026
110	2.2206	2.318	2.421	0.07373	2.2732	2.3844	2.4773	0.073588	0.0526	0.0664	0.0936	0.016112

Device Test: 41.3 I_SS(SoftStart|ChargeCurrent/SS3/7/7///90.9/634//0///@I_SS)





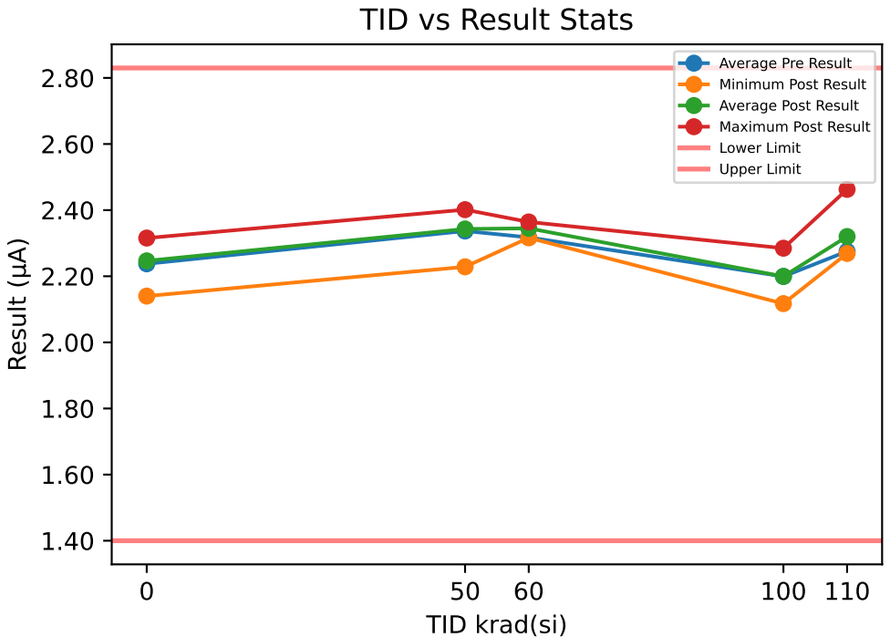
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

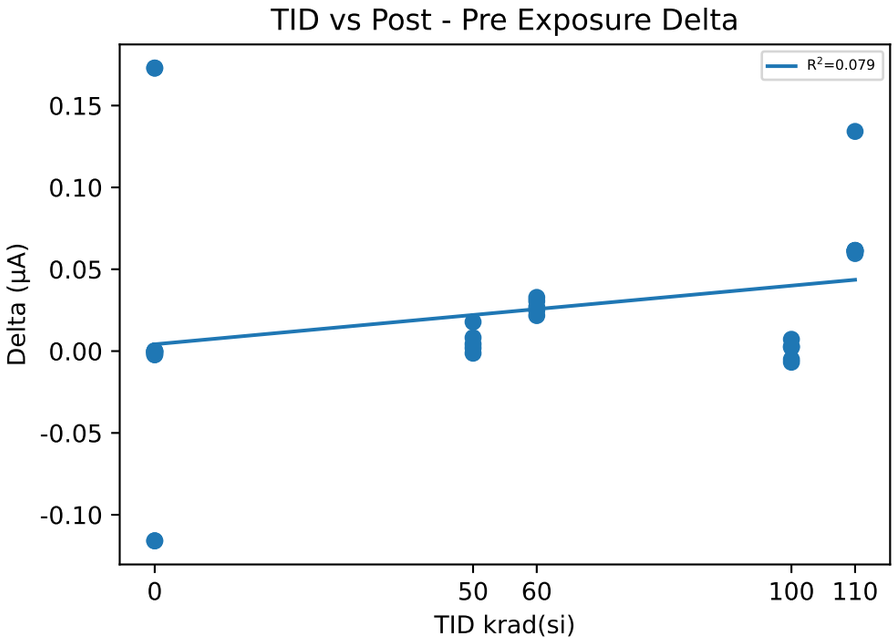
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4402	2.469	0.0288
2	0	CU2	2.3352	2.3618	0.0266
3	0	CU3	2.3129	2.3401	0.0272
11	50	Unbiased-50k	2.3044	2.3456	0.0412
12	50	Unbiased-50k	2.3261	2.3658	0.0397
13	50	Unbiased-50k	2.3136	2.3481	0.0345
14	50	Unbiased-50k	2.3577	2.3995	0.0418
16	50	Unbiased-50k	2.3823	2.4129	0.0306
17	60	Biased-50k	2.4246	2.4973	0.0727
18	60	Biased-50k	2.2733	2.3298	0.0565
19	60	Biased-50k	2.4498	2.5147	0.0649
20	60	Biased-50k	2.3616	2.4327	0.0711
21	60	Biased-50k	2.2234	2.2875	0.0641
24	100	Unbiased-100k	2.1995	2.1983	-0.0012
25	100	Unbiased-100k	2.3339	2.3376	0.0037
26	100	Unbiased-100k	2.2074	2.2155	0.0081
27	100	Unbiased-100k	2.1551	2.1629	0.0078
28	100	Unbiased-100k	2.3162	2.3211	0.0049
29	110	Biased-100k	2.2196	2.2753	0.0557
30	110	Biased-100k	2.4259	2.4948	0.0689
31	110	Biased-100k	2.2137	2.268	0.0543
32	110	Biased-100k	2.3036	2.4451	0.1415
34	110	Biased-100k	2.2704	2.3273	0.0569

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3129	2.3628	2.4402	0.06798	2.3401	2.3903	2.469	0.069014	0.0266	0.027533	0.0288	0.0011372
50	2.3044	2.3368	2.3823	0.032441	2.3456	2.3744	2.4129	0.030444	0.0306	0.03756	0.0418	0.0048377
60	2.2234	2.3465	2.4498	0.096838	2.2875	2.4124	2.5147	0.10063	0.0565	0.06586	0.0727	0.0064396
100	2.1551	2.2424	2.3339	0.078271	2.1629	2.2471	2.3376	0.077679	-0.0012	0.00466	0.0081	0.0037753
110	2.2137	2.2866	2.4259	0.086254	2.268	2.3621	2.4948	0.10259	0.0543	0.07546	0.1415	0.037373

Device Test: 41.4 I_SS(SoftStart|ChargeCurrent/SS4/7/7///90.9/634//0///@I_SS)





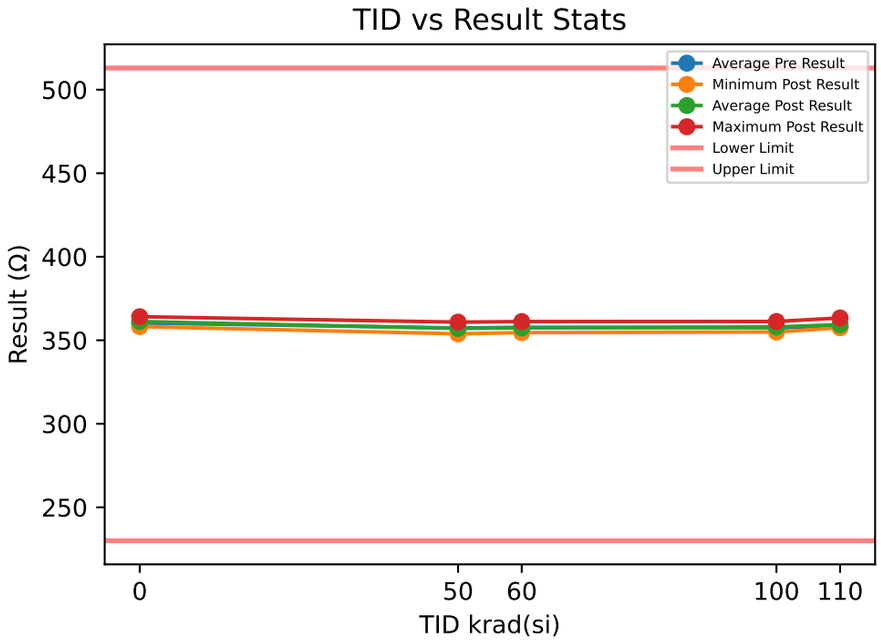
Test Results (Lower Limit = 1.4, Upper Limit = 2.83 (µA))

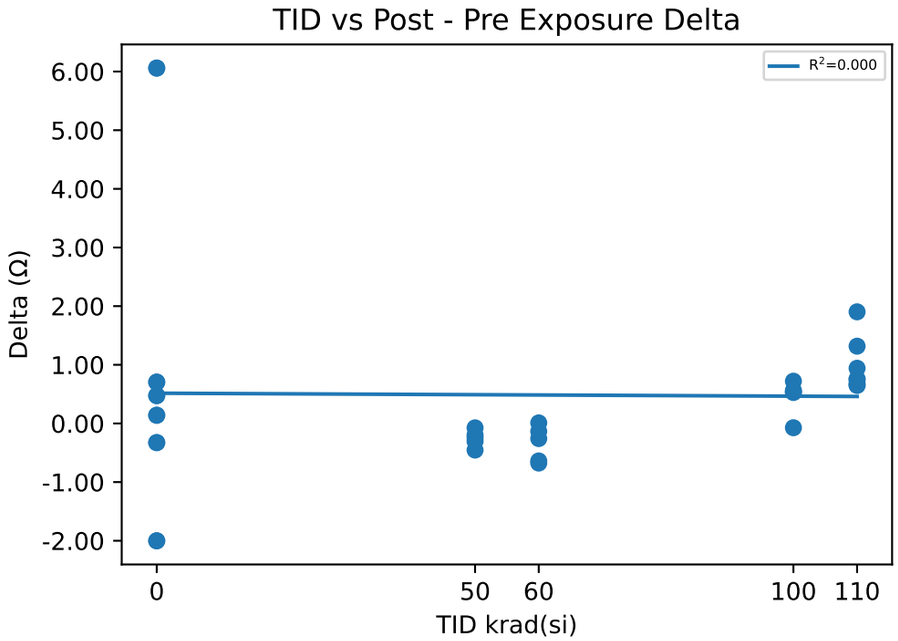
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3156	2.3146	-0.001
2	0	CU2	2.1413	2.1414	0.0001
3	0	CU3	2.2559	2.2537	-0.0022
11	50	Unbiased-50k	2.3275	2.3357	0.0082
12	50	Unbiased-50k	2.3872	2.3915	0.0043
13	50	Unbiased-50k	2.2298	2.2285	-0.0013
14	50	Unbiased-50k	2.3836	2.4014	0.0178
16	50	Unbiased-50k	2.3561	2.358	0.0019
17	60	Biased-50k	2.3267	2.3595	0.0328
18	60	Biased-50k	2.3138	2.3355	0.0217
19	60	Biased-50k	2.2915	2.3163	0.0248
20	60	Biased-50k	2.3223	2.3493	0.027
21	60	Biased-50k	2.3336	2.3642	0.0306
24	100	Unbiased-100k	2.2898	2.2848	-0.005
25	100	Unbiased-100k	2.1568	2.164	0.0072
26	100	Unbiased-100k	2.1509	2.1538	0.0029
27	100	Unbiased-100k	2.1149	2.1172	0.0023
28	100	Unbiased-100k	2.2844	2.2776	-0.0068
29	110	Biased-100k	2.2454	2.3059	0.0605
30	110	Biased-100k	2.4017	2.4628	0.0611
31	110	Biased-100k	2.2565	2.3161	0.0596
32	110	Biased-100k	2.2659	2.4001	0.1342
34	110	Biased-100k	2.2076	2.2691	0.0615

Test Statistics (µA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1413	2.2376	2.3156	0.088579	2.1414	2.2366	2.3146	0.087862	-0.0022	-0.0010333	0.0001	0.0011504
50	2.2298	2.3368	2.3872	0.064495	2.2285	2.343	2.4014	0.069194	-0.0013	0.00618	0.0178	0.0073639
60	2.2915	2.3176	2.3336	0.016252	2.3163	2.345	2.3642	0.019438	0.0217	0.02738	0.0328	0.0044387
100	2.1149	2.1994	2.2898	0.081707	2.1172	2.1995	2.2848	0.076645	-0.0068	0.00012	0.0072	0.0058461
110	2.2076	2.2754	2.4017	0.073986	2.2691	2.3508	2.4628	0.07885	0.0596	0.07538	0.1342	0.032889

Device Test: 41.5 R_SS_DISCHARGE(SoftStart|Resistance/SS1/7/7///90.9/634//0///@R_SS_DISCHARGE)





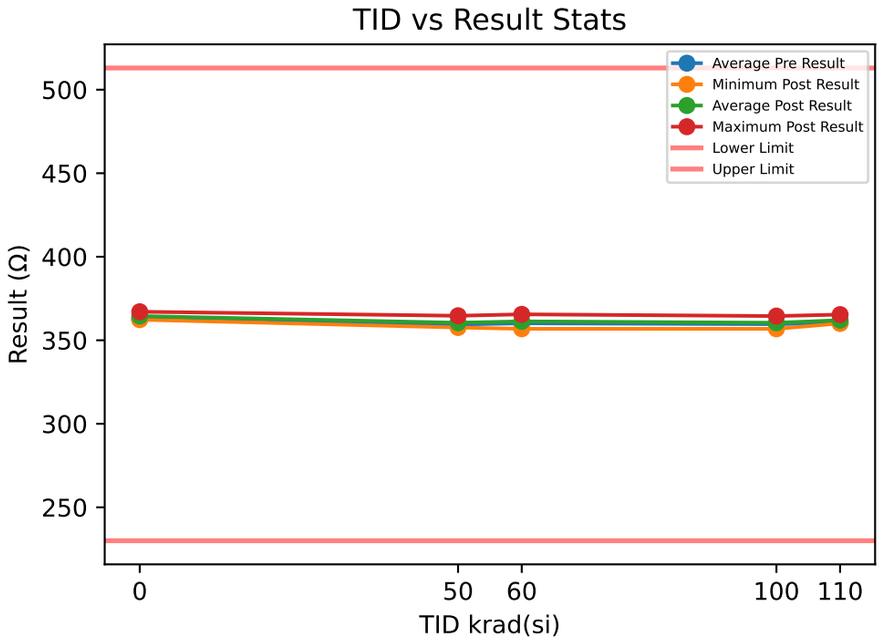
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

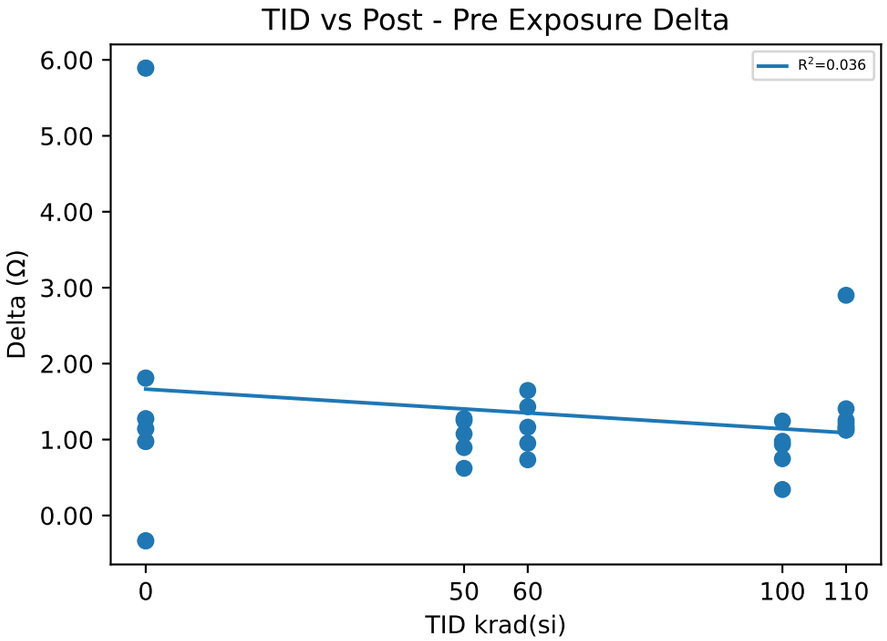
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	362.04	361.72	-0.3268
2	0	CU2	358.04	358.18	0.1398
3	0	CU3	361.04	361.74	0.7044
11	50	Unbiased-50k	358.14	357.95	-0.1967
12	50	Unbiased-50k	357.16	356.92	-0.2457
13	50	Unbiased-50k	354.3	353.85	-0.4538
14	50	Unbiased-50k	356.09	355.79	-0.3054
16	50	Unbiased-50k	360.93	360.86	-0.0749
17	60	Biased-50k	360.21	359.57	-0.639
18	60	Biased-50k	354.84	354.58	-0.258
19	60	Biased-50k	355.72	355.72	0.0094
20	60	Biased-50k	356.57	355.9	-0.6757
21	60	Biased-50k	361.32	361.19	-0.1346
24	100	Unbiased-100k	358.95	359.67	0.7204
25	100	Unbiased-100k	354.42	354.95	0.5276
26	100	Unbiased-100k	357.07	357.6	0.5362
27	100	Unbiased-100k	356.45	356.38	-0.0731
28	100	Unbiased-100k	360.68	361.25	0.5642
29	110	Biased-100k	356.56	357.5	0.9414
30	110	Biased-100k	362.65	363.35	0.6934
31	110	Biased-100k	358.3	359.61	1.3174
32	110	Biased-100k	355.7	357.6	1.9029
34	110	Biased-100k	358.45	359.1	0.6511

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	358.04	360.38	362.04	2.0813	358.18	360.55	361.74	2.0478	-0.3268	0.17247	0.7044	0.51638
50	354.3	357.33	360.93	2.4673	353.85	357.07	360.86	2.6051	-0.4538	-0.2553	-0.0749	0.13963
60	354.84	357.73	361.32	2.863	354.58	357.39	361.19	2.8307	-0.6757	-0.33958	0.0094	0.3054
100	354.42	357.51	360.68	2.3979	354.95	357.97	361.25	2.5213	-0.0731	0.45506	0.7204	0.30542
110	355.7	358.33	362.65	2.6815	357.5	359.43	363.35	2.3744	0.6511	1.1012	1.9029	0.52055

Device Test: 41.6 R_SS_DISCHARGE(SoftStart|Resistance/SS2/7/7///90.9/634//0///@R_SS_DISCHARGE)





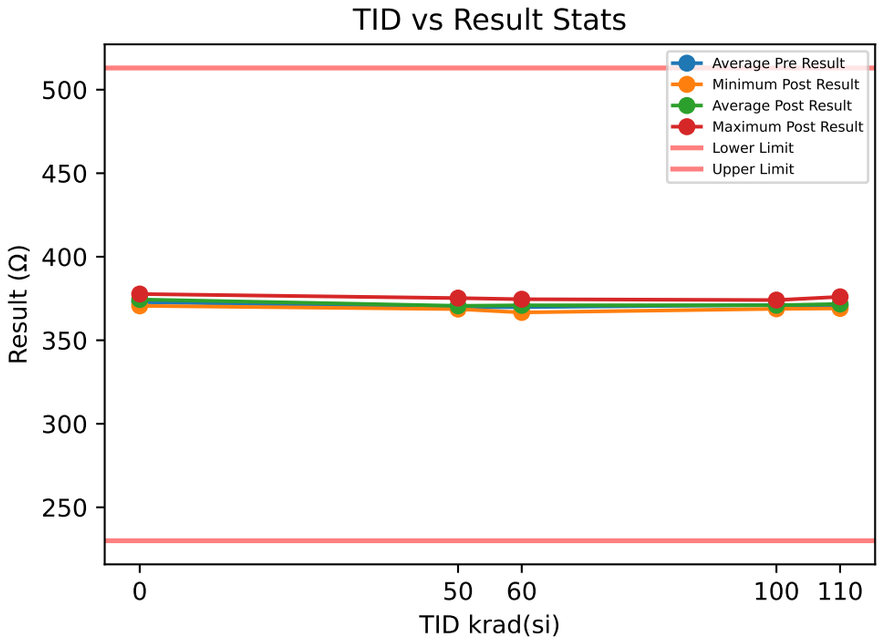
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

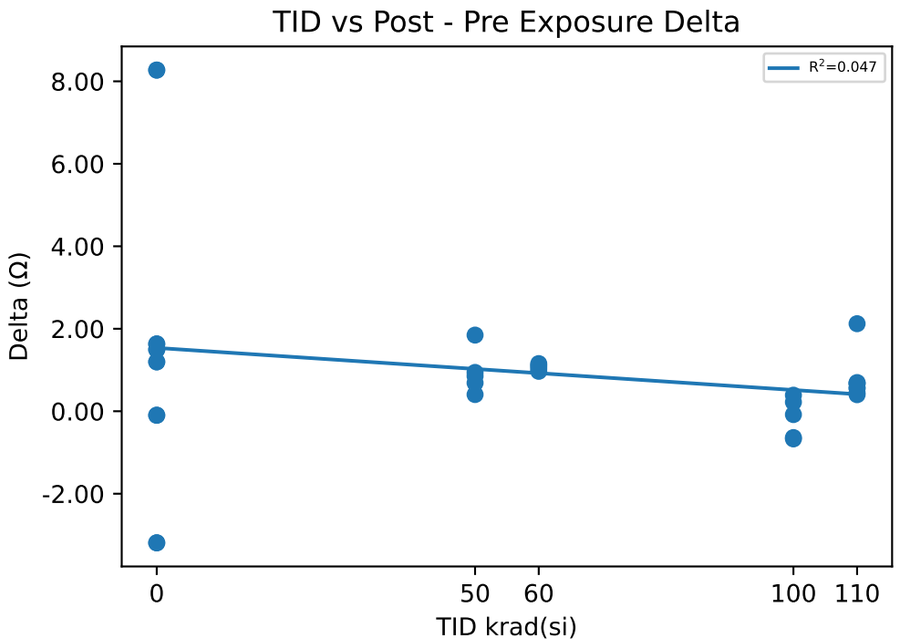
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	364.1	365.07	0.974
2	0	CU2	361.17	362.32	1.1417
3	0	CU3	362.82	364.63	1.8096
11	50	Unbiased-50k	360.16	361.05	0.8943
12	50	Unbiased-50k	359.12	360.19	1.0745
13	50	Unbiased-50k	357.01	357.63	0.6212
14	50	Unbiased-50k	357.65	358.92	1.2764
16	50	Unbiased-50k	363.41	364.66	1.2494
17	60	Biased-50k	362.03	363.19	1.1627
18	60	Biased-50k	355.91	356.86	0.9518
19	60	Biased-50k	358.66	360.3	1.6464
20	60	Biased-50k	359.29	360.72	1.4321
21	60	Biased-50k	364.79	365.52	0.7335
24	100	Unbiased-100k	361.19	362.43	1.2432
25	100	Unbiased-100k	355.92	356.85	0.9346
26	100	Unbiased-100k	359.41	359.75	0.3422
27	100	Unbiased-100k	358.11	358.86	0.7475
28	100	Unbiased-100k	363.51	364.49	0.9765
29	110	Biased-100k	358.83	360.08	1.2556
30	110	Biased-100k	364.15	365.36	1.2169
31	110	Biased-100k	360.3	361.7	1.4055
32	110	Biased-100k	358.21	361.11	2.8999
34	110	Biased-100k	360.82	361.95	1.1247

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	361.17	362.7	364.1	1.4656	362.32	364	365.07	1.4795	0.974	1.3084	1.8096	0.44205
50	357.01	359.47	363.41	2.5253	357.63	360.49	364.66	2.666	0.6212	1.0232	1.2764	0.27209
60	355.91	360.13	364.79	3.3894	356.86	361.32	365.52	3.2553	0.7335	1.1853	1.6464	0.36492
100	355.92	359.63	363.51	2.9	356.85	360.48	364.49	3.0084	0.3422	0.8488	1.2432	0.33396
110	358.21	360.46	364.15	2.3176	360.08	362.04	365.36	1.9917	1.1247	1.5805	2.8999	0.74447

Device Test: 41.7 R_SS_DISCHARGE(SoftStart|Resistance/SS3/7/7///90.9/634//0///@R_SS_DISCHARGE)





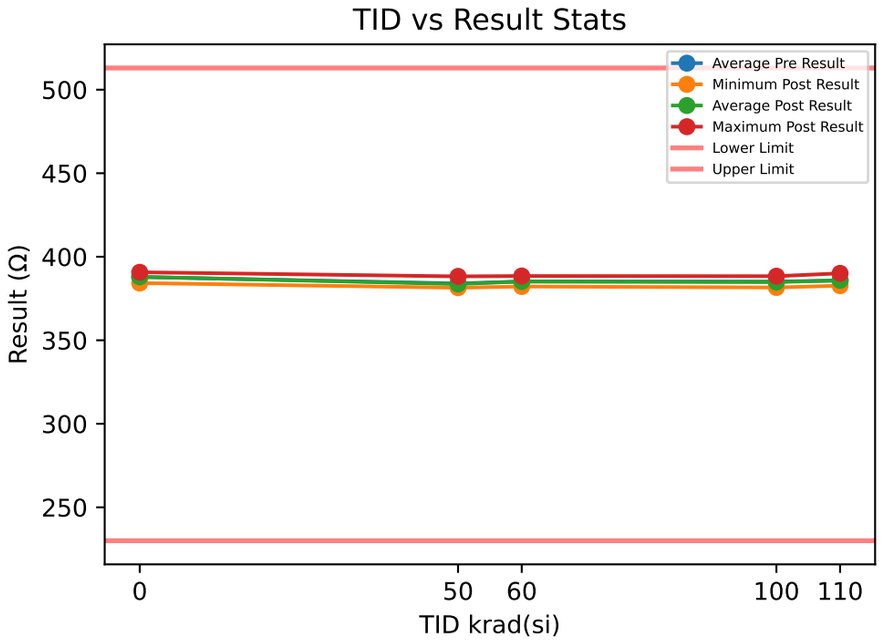
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

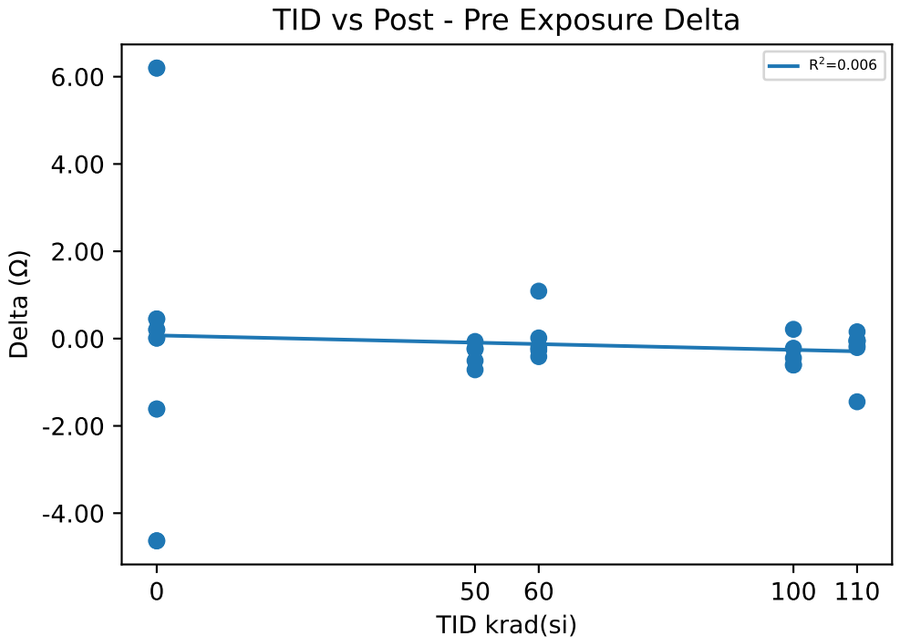
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	375.37	376.86	1.4962
2	0	CU2	369.4	370.6	1.1975
3	0	CU3	373.8	375.43	1.6319
11	50	Unbiased-50k	369.25	370.19	0.9408
12	50	Unbiased-50k	368.79	369.48	0.6864
13	50	Unbiased-50k	368.25	368.65	0.405
14	50	Unbiased-50k	368.68	369.54	0.8527
16	50	Unbiased-50k	373.4	375.24	1.8464
17	60	Biased-50k	371.68	372.76	1.0772
18	60	Biased-50k	365.68	366.65	0.9683
19	60	Biased-50k	369	370.12	1.1176
20	60	Biased-50k	369.46	370.48	1.0272
21	60	Biased-50k	373.41	374.57	1.1551
24	100	Unbiased-100k	371.59	371.98	0.389
25	100	Unbiased-100k	369.44	368.8	-0.6384
26	100	Unbiased-100k	370.2	369.53	-0.6709
27	100	Unbiased-100k	370.54	370.46	-0.0807
28	100	Unbiased-100k	373.84	374.06	0.221
29	110	Biased-100k	368.65	369.05	0.4014
30	110	Biased-100k	375.56	376	0.445
31	110	Biased-100k	369.56	370.26	0.6952
32	110	Biased-100k	367.69	369.82	2.1227
34	110	Biased-100k	371.52	372.08	0.5619

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	369.4	372.85	375.37	3.0902	370.6	374.3	376.86	3.2798	1.1975	1.4419	1.6319	0.22224
50	368.25	369.67	373.4	2.1118	368.65	370.62	375.24	2.6418	0.405	0.94626	1.8464	0.54303
60	365.68	369.85	373.41	2.9275	366.65	370.92	374.57	2.989	0.9683	1.0691	1.1551	0.073706
100	369.44	371.12	373.84	1.7038	368.8	370.97	374.06	2.0975	-0.6709	-0.156	0.389	0.48545
110	367.69	370.6	375.56	3.1116	369.05	371.44	376	2.7816	0.4014	0.84524	2.1227	0.72317

Device Test: 41.8 R_SS_DISCHARGE(SoftStart|Resistance/SS4/7/7///90.9/634//0///@R_SS_DISCHARGE)





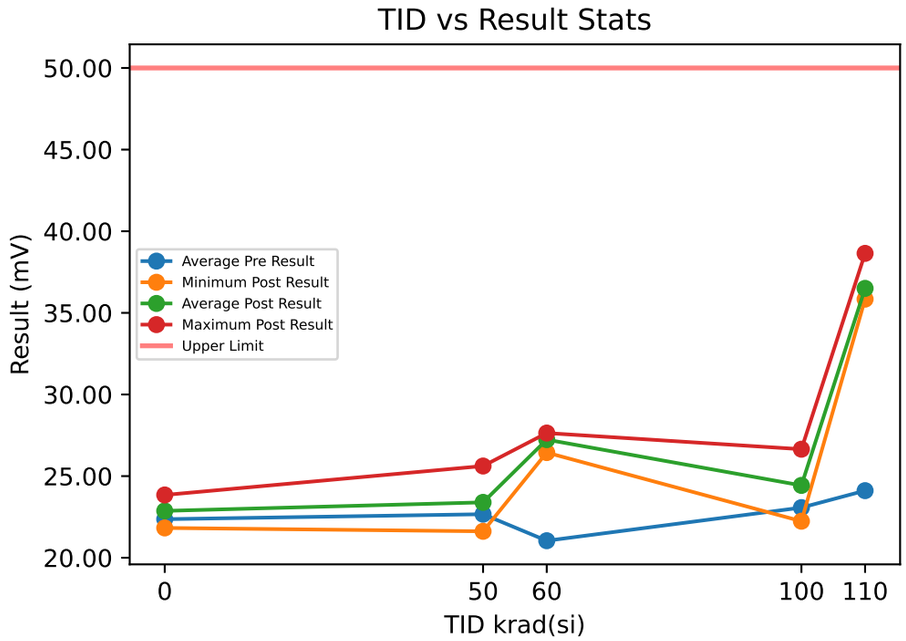
Test Results (Lower Limit = 230.0, Upper Limit = 513.0 (Ω))

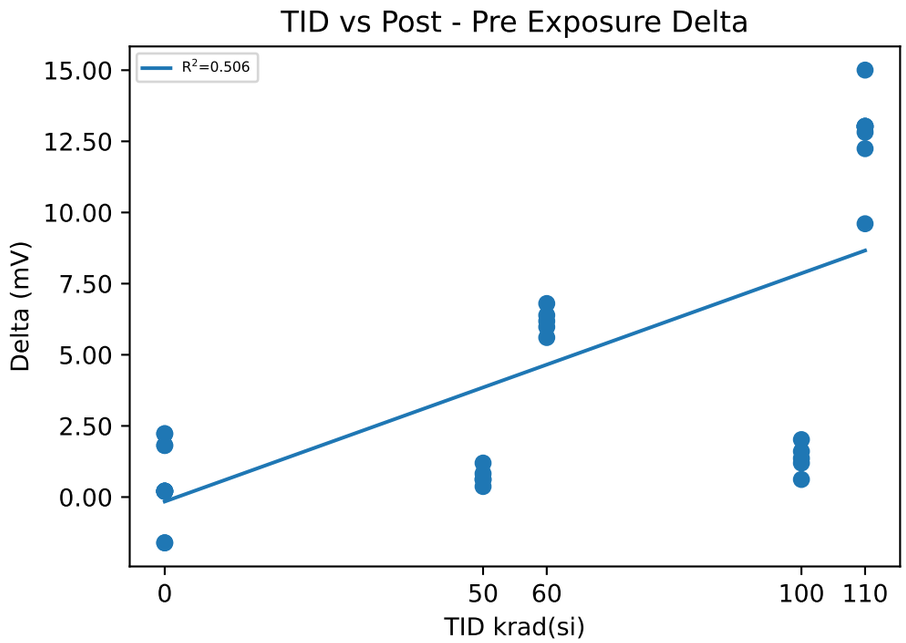
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	390.49	388.87	-1.6136
2	0	CU2	384.25	384.26	0.0116
3	0	CU3	388.88	389.33	0.4497
11	50	Unbiased-50k	383.23	383	-0.2273
12	50	Unbiased-50k	383.33	382.82	-0.5062
13	50	Unbiased-50k	382.18	381.46	-0.7148
14	50	Unbiased-50k	383.03	382.78	-0.2443
16	50	Unbiased-50k	388.3	388.24	-0.0662
17	60	Biased-50k	386.74	386.48	-0.2682
18	60	Biased-50k	382.39	382.18	-0.2093
19	60	Biased-50k	383.63	384.72	1.087
20	60	Biased-50k	384.56	384.15	-0.4134
21	60	Biased-50k	388.44	388.46	0.015
24	100	Unbiased-100k	386.08	385.86	-0.2209
25	100	Unbiased-100k	382.22	381.61	-0.6055
26	100	Unbiased-100k	382.8	382.19	-0.6025
27	100	Unbiased-100k	385.77	385.98	0.2122
28	100	Unbiased-100k	388.8	388.36	-0.4457
29	110	Biased-100k	382.88	382.68	-0.2055
30	110	Biased-100k	391.5	390.06	-1.4478
31	110	Biased-100k	384.62	384.77	0.1564
32	110	Biased-100k	383.34	383.17	-0.1661
34	110	Biased-100k	386.61	386.54	-0.066

Test Statistics (Ω)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	384.25	387.87	390.49	3.2395	384.26	387.49	389.33	2.8046	-1.6136	-0.3841	0.4497	1.0871
50	382.18	384.01	388.3	2.4408	381.46	383.66	388.24	2.6307	-0.7148	-0.35176	-0.0662	0.25702
60	382.39	385.15	388.44	2.432	382.18	385.2	388.46	2.3825	-0.4134	0.04222	1.087	0.60405
100	382.22	385.13	388.8	2.6798	381.61	384.8	388.36	2.8338	-0.6055	-0.33248	0.2122	0.34256
110	382.88	385.79	391.5	3.5053	382.68	385.44	390.06	2.9889	-1.4478	-0.3458	0.1564	0.63184

Device Test: 41.9 V_SS_START(SoftStart|MaxStartupVoltage/SS1/7/7///90.9/634//0///@V_SS_START)





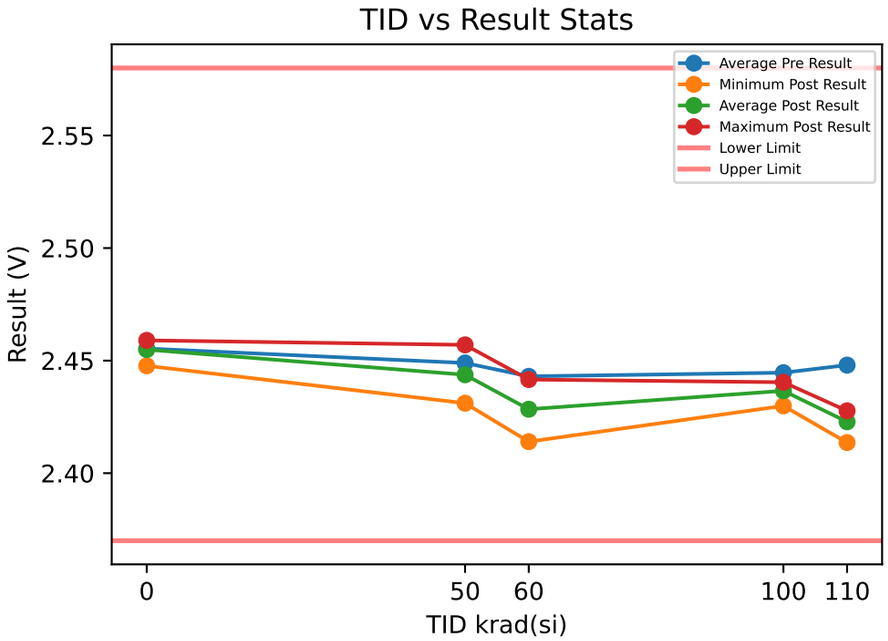
Test Results (Upper Limit = 50.0 (mV))

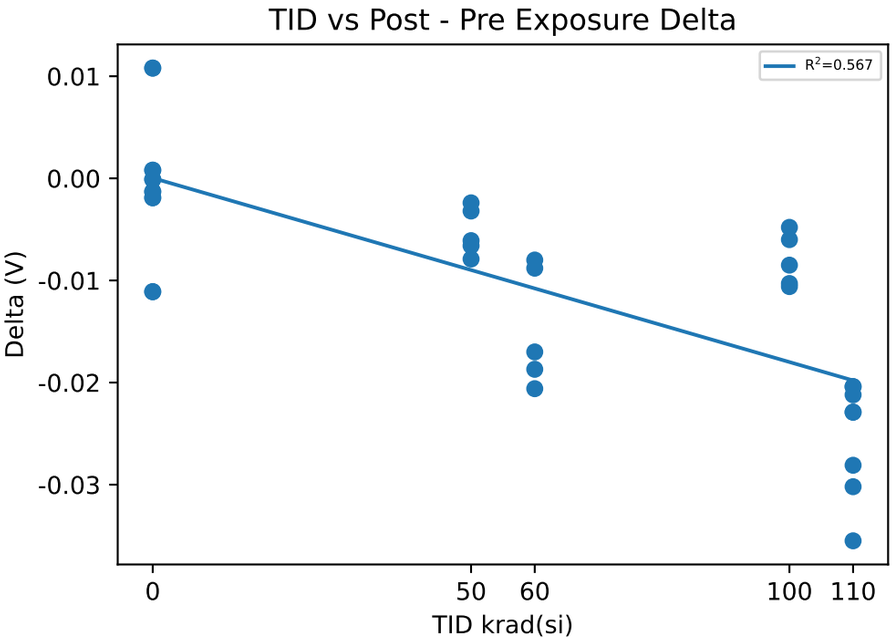
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	21.826	22.032	0.2061
2	0	CU2	23.64	23.846	0.2061
3	0	CU3	21.62	21.826	0.2061
11	50	Unbiased-50k	21.414	22.032	0.6183
12	50	Unbiased-50k	25.247	25.618	0.3709
13	50	Unbiased-50k	21.62	22.238	0.6183
14	50	Unbiased-50k	20.424	21.62	1.1953
16	50	Unbiased-50k	24.629	25.453	0.8244
17	60	Biased-50k	21.249	27.226	5.9768
18	60	Biased-50k	20.837	26.442	5.6058
19	60	Biased-50k	21.249	27.638	6.389
20	60	Biased-50k	20.837	27.638	6.8012
21	60	Biased-50k	21.043	27.226	6.1829
24	100	Unbiased-100k	22.856	24.217	1.3603
25	100	Unbiased-100k	21.62	23.227	1.6076
26	100	Unbiased-100k	24.629	26.648	2.0197
27	100	Unbiased-100k	21.62	22.238	0.6183
28	100	Unbiased-100k	24.629	25.824	1.1953
29	110	Biased-100k	23.227	36.047	12.819
30	110	Biased-100k	24.217	36.459	12.242
31	110	Biased-100k	23.64	38.644	15.004
32	110	Biased-100k	26.236	35.84	9.6042
34	110	Biased-100k	23.227	36.253	13.025

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.62	22.362	23.64	1.1114	21.826	22.568	23.846	1.1114	0.2061	0.2061	0.2061	0
50	20.424	22.667	25.247	2.1332	21.62	23.392	25.618	1.9702	0.3709	0.72544	1.1953	0.3079
60	20.837	21.043	21.249	0.2061	26.442	27.234	27.638	0.48808	5.6058	6.1911	6.8012	0.4472
100	21.62	23.071	24.629	1.5093	22.238	24.431	26.648	1.814	0.6183	1.3602	2.0197	0.51811
110	23.227	24.109	26.236	1.2562	35.84	36.648	38.644	1.1388	9.6042	12.539	15.004	1.9425

Device Test: 42.1 UVLO_RISE_PVIN(THRESHOLD|RISE/PVIN1////90.9/634//0///@UVLO_RISE_PVIN)





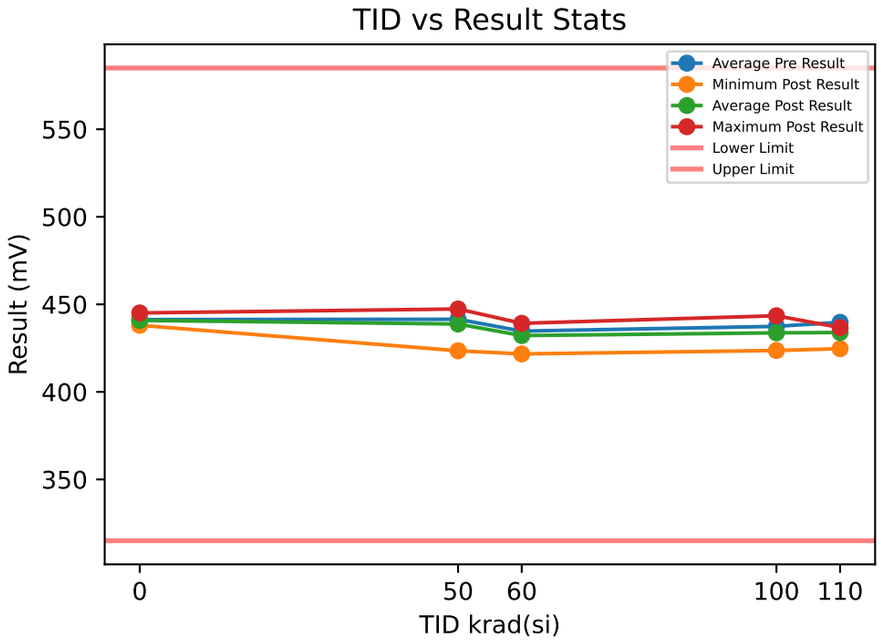
Test Results (Lower Limit = 2.37, Upper Limit = 2.58 (V))

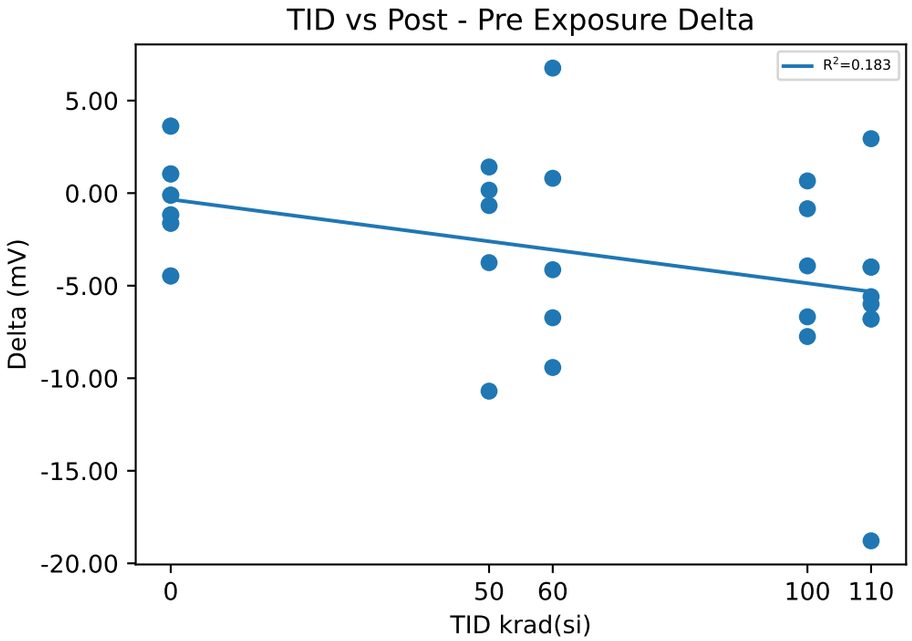
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4601	2.4582	-0.0019
2	0	CU2	2.4469	2.4477	0.0008
3	0	CU3	2.4591	2.459	-0.0001
11	50	Unbiased-50k	2.4602	2.457	-0.0032
12	50	Unbiased-50k	2.4442	2.4418	-0.0024
13	50	Unbiased-50k	2.4475	2.4409	-0.0066
14	50	Unbiased-50k	2.439	2.4311	-0.0079
16	50	Unbiased-50k	2.4539	2.4478	-0.0061
17	60	Biased-50k	2.4395	2.4307	-0.0088
18	60	Biased-50k	2.4483	2.4296	-0.0187
19	60	Biased-50k	2.4346	2.414	-0.0206
20	60	Biased-50k	2.4431	2.4261	-0.017
21	60	Biased-50k	2.4496	2.4416	-0.008
24	100	Unbiased-100k	2.4488	2.4403	-0.0085
25	100	Unbiased-100k	2.4464	2.4404	-0.006
26	100	Unbiased-100k	2.4347	2.4299	-0.0048
27	100	Unbiased-100k	2.4472	2.4366	-0.0106
28	100	Unbiased-100k	2.4461	2.4358	-0.0103
29	110	Biased-100k	2.4485	2.4204	-0.0281
30	110	Biased-100k	2.4456	2.4244	-0.0212
31	110	Biased-100k	2.4491	2.4136	-0.0355
32	110	Biased-100k	2.4487	2.4185	-0.0302
34	110	Biased-100k	2.4481	2.4252	-0.0229

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.4469	2.4554	2.4601	0.0073494	2.4477	2.455	2.459	0.0063058	-0.0019	-0.0004	0.0008	0.0013748
50	2.439	2.449	2.4602	0.0082875	2.4311	2.4437	2.457	0.0095382	-0.0079	-0.00524	-0.0024	0.0023394
60	2.4346	2.443	2.4496	0.0062143	2.414	2.4284	2.4416	0.0099199	-0.0206	-0.01462	-0.008	0.005826
100	2.4347	2.4446	2.4488	0.0056545	2.4299	2.4366	2.4404	0.0042913	-0.0106	-0.00804	-0.0048	0.0025755
110	2.4456	2.448	2.4491	0.0013892	2.4136	2.4204	2.4252	0.004714	-0.0355	-0.02758	-0.0212	0.0057547

Device Test: 42.10 UVLO_HYST_PVIN(THRESHOLD|HYST/PVIN2/////90.9/634//0///@UVLO_HYST_PVIN)





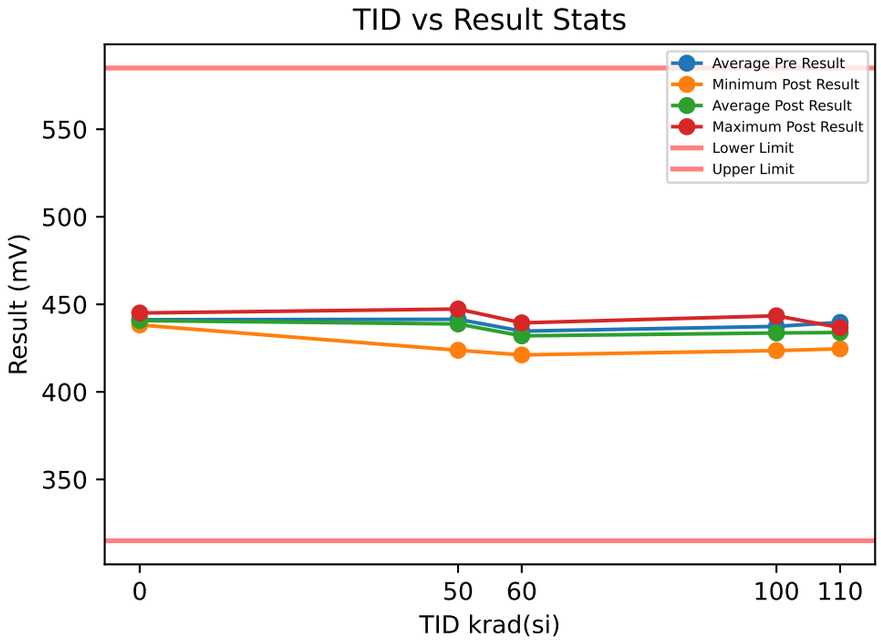
Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

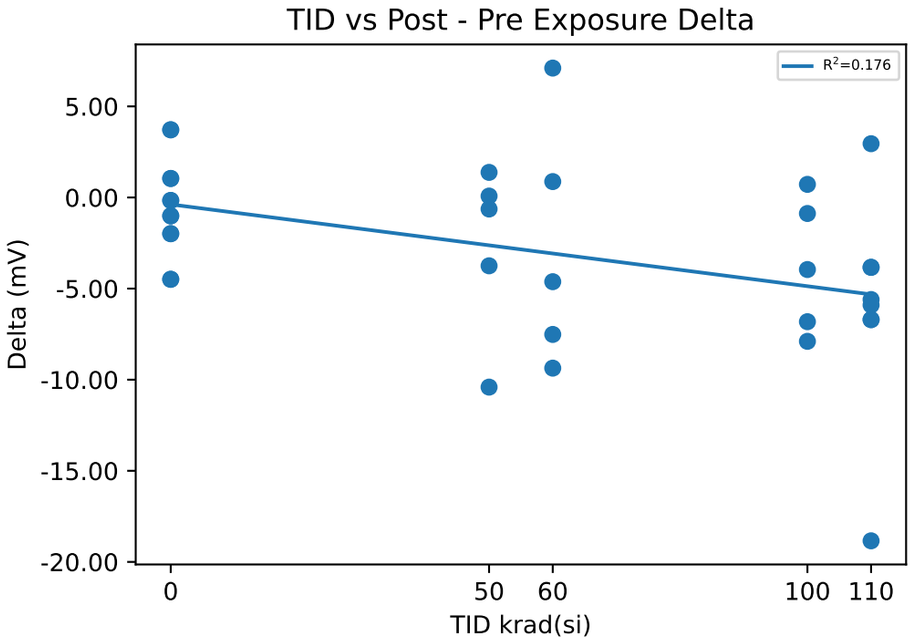
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	441.47	441.36	-0.1107
2	0	CU2	439.2	438.03	-1.1739
3	0	CU3	443.2	441.57	-1.6255
11	50	Unbiased-50k	445.95	447.36	1.4122
12	50	Unbiased-50k	439.14	438.47	-0.6706
13	50	Unbiased-50k	445.16	441.4	-3.7561
14	50	Unbiased-50k	434.18	423.48	-10.699
16	50	Unbiased-50k	442.96	443.12	0.1597
17	60	Biased-50k	432.41	439.16	6.756
18	60	Biased-50k	442.25	432.83	-9.4198
19	60	Biased-50k	425.82	421.68	-4.138
20	60	Biased-50k	441.29	434.56	-6.7328
21	60	Biased-50k	431.82	432.63	0.8017
24	100	Unbiased-100k	438.53	439.19	0.659
25	100	Unbiased-100k	441.16	434.47	-6.6823
26	100	Unbiased-100k	424.49	423.65	-0.8424
27	100	Unbiased-100k	447.41	443.48	-3.9297
28	100	Unbiased-100k	435.54	427.79	-7.7469
29	110	Biased-100k	439.14	433.15	-5.9952
30	110	Biased-100k	441.74	436.15	-5.5938
31	110	Biased-100k	443.46	424.68	-18.784
32	110	Biased-100k	433.79	436.74	2.9416
34	110	Biased-100k	440.57	433.78	-6.7972

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	439.2	441.29	443.2	2.0048	438.03	440.32	441.57	1.9889	-1.6255	-0.97003	-0.1107	0.77771
50	434.18	441.48	445.95	4.8585	423.48	438.77	447.36	9.1296	-10.699	-2.7107	1.4122	4.8554
60	425.82	434.72	442.25	6.9437	421.68	432.17	439.16	6.4289	-9.4198	-2.5466	6.756	6.4235
100	424.49	437.42	447.41	8.4505	423.65	433.72	443.48	8.0969	-7.7469	-3.7085	0.659	3.6225
110	433.79	439.74	443.46	3.6822	424.68	432.9	436.74	4.84	-18.784	-6.8457	2.9416	7.7556

Device Test: 42.11 UVLO_HYST_PVIN(THRESHOLD|HYST/PVIN3/////90.9/634//0///@UVLO_HYST_PVIN)





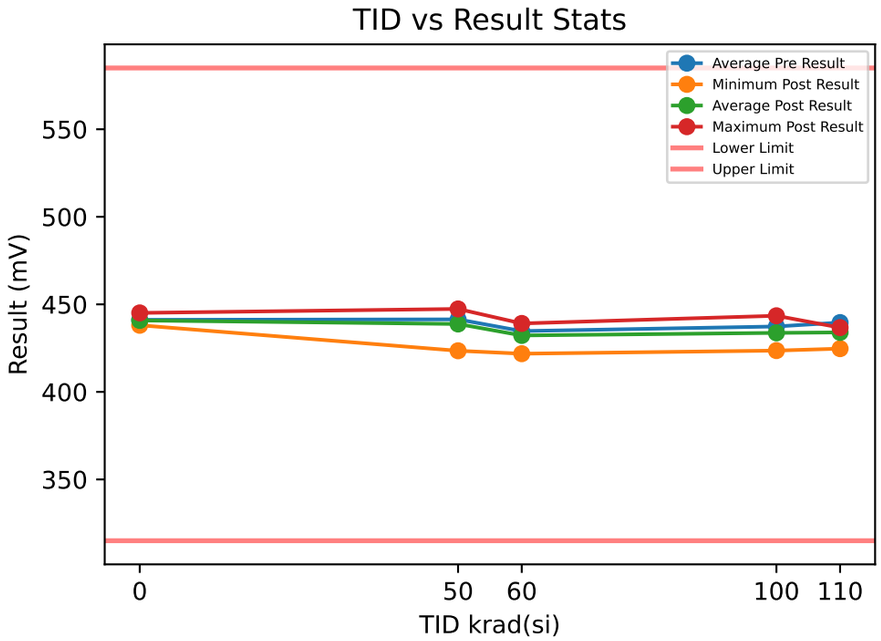
Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

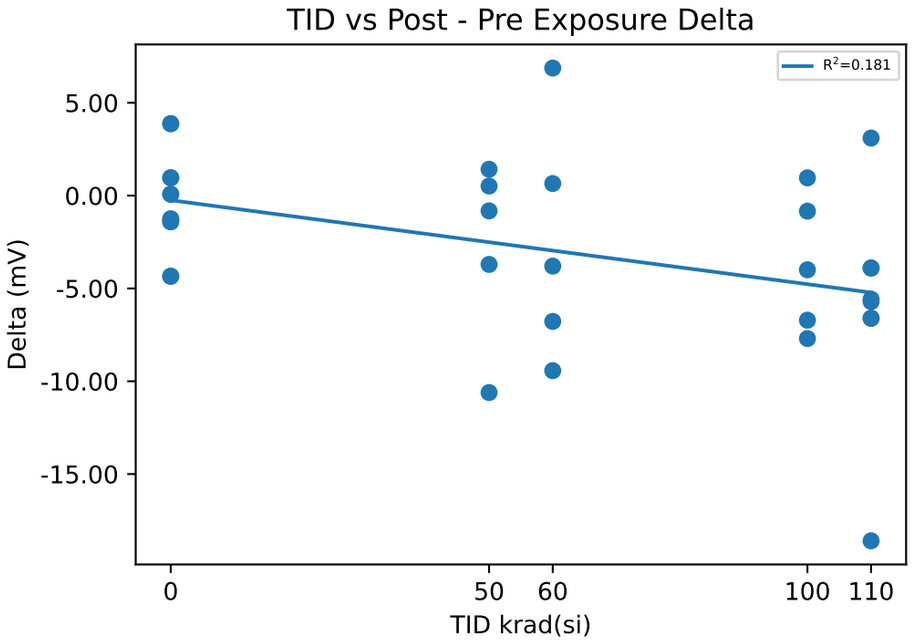
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	441.35	441.18	-0.1633
2	0	CU2	439.25	438.24	-1.0089
3	0	CU3	443.07	441.08	-1.9867
11	50	Unbiased-50k	445.95	447.33	1.3777
12	50	Unbiased-50k	439.18	438.54	-0.6334
13	50	Unbiased-50k	445.1	441.35	-3.7496
14	50	Unbiased-50k	434.17	423.77	-10.407
16	50	Unbiased-50k	442.89	442.97	0.0777
17	60	Biased-50k	432.31	439.41	7.102
18	60	Biased-50k	442.24	432.88	-9.3654
19	60	Biased-50k	425.74	421.12	-4.6218
20	60	Biased-50k	441.4	433.88	-7.5163
21	60	Biased-50k	431.86	432.73	0.8726
24	100	Unbiased-100k	438.38	439.1	0.7194
25	100	Unbiased-100k	441.23	434.41	-6.8169
26	100	Unbiased-100k	424.46	423.58	-0.8786
27	100	Unbiased-100k	447.41	443.46	-3.954
28	100	Unbiased-100k	435.57	427.68	-7.8953
29	110	Biased-100k	439	433.1	-5.9039
30	110	Biased-100k	441.74	436.14	-5.6008
31	110	Biased-100k	443.44	424.59	-18.843
32	110	Biased-100k	433.79	436.74	2.9515
34	110	Biased-100k	440.48	433.78	-6.7031

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	439.25	441.22	443.07	1.9127	438.24	440.17	441.18	1.6706	-1.9867	-1.053	-0.1633	0.9125
50	434.17	441.46	445.95	4.842	423.77	438.79	447.33	8.9817	-10.407	-2.667	1.3777	4.7201
60	425.74	434.71	442.24	6.9976	421.12	432	439.41	6.6765	-9.3654	-2.7058	7.102	6.7112
100	424.46	437.41	447.41	8.4653	423.58	433.65	443.46	8.117	-7.8953	-3.7651	0.7194	3.7031
110	433.79	439.69	443.44	3.6804	424.59	432.87	436.74	4.8753	-18.843	-6.8198	2.9515	7.7841

Device Test: 42.12 UVLO_HYST_PVIN(THRESHOLD|HYST/PVIN4/////90.9/634//0///@UVLO_HYST_PVIN)





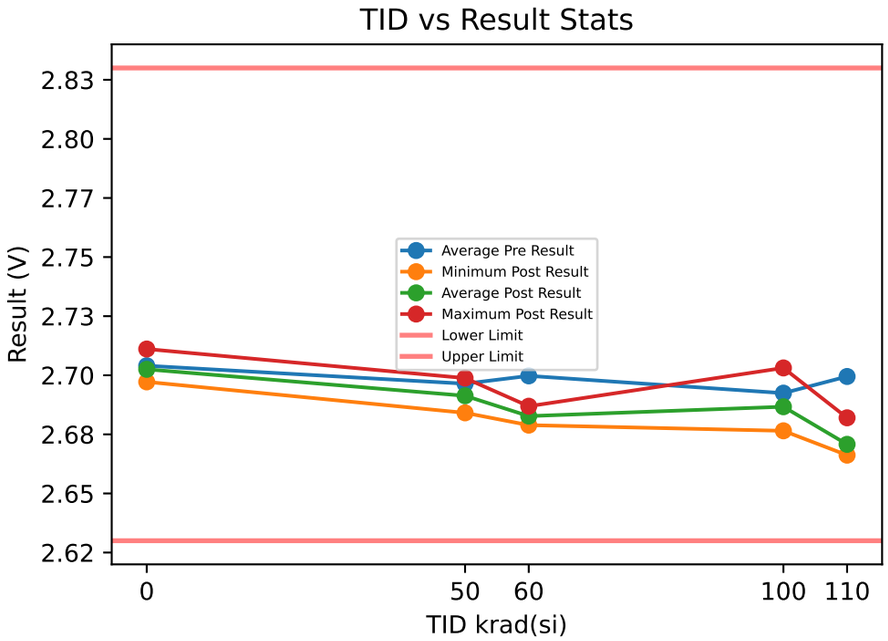
Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

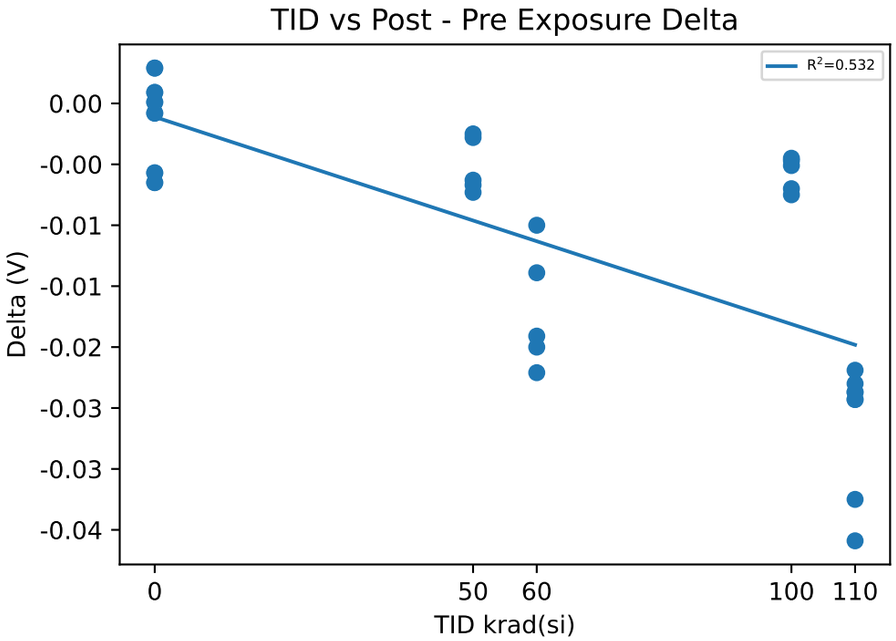
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	441.24	441.31	0.077
2	0	CU2	439.31	438.05	-1.2567
3	0	CU3	442.93	441.52	-1.4069
11	50	Unbiased-50k	445.96	447.38	1.4192
12	50	Unbiased-50k	439.26	438.43	-0.8228
13	50	Unbiased-50k	445.11	441.41	-3.7076
14	50	Unbiased-50k	434.1	423.49	-10.61
16	50	Unbiased-50k	442.69	443.2	0.5144
17	60	Biased-50k	432.22	439.09	6.8696
18	60	Biased-50k	442.42	432.99	-9.4295
19	60	Biased-50k	425.62	421.82	-3.7989
20	60	Biased-50k	441.39	434.62	-6.7763
21	60	Biased-50k	432.04	432.69	0.6502
24	100	Unbiased-100k	438.24	439.2	0.9553
25	100	Unbiased-100k	441.11	434.4	-6.7112
26	100	Unbiased-100k	424.42	423.58	-0.8371
27	100	Unbiased-100k	447.47	443.48	-3.9961
28	100	Unbiased-100k	435.56	427.86	-7.701
29	110	Biased-100k	438.8	433.09	-5.7098
30	110	Biased-100k	441.75	436.17	-5.5816
31	110	Biased-100k	443.29	424.69	-18.596
32	110	Biased-100k	433.61	436.71	3.1004
34	110	Biased-100k	440.54	433.93	-6.605

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	439.31	441.16	442.93	1.8111	438.05	440.3	441.52	1.9463	-1.4069	-0.8622	0.077	0.81683
50	434.1	441.42	445.96	4.8511	423.49	438.78	447.38	9.1421	-10.61	-2.6413	1.4192	4.8577
60	425.62	434.74	442.42	7.075	421.82	432.24	439.09	6.3637	-9.4295	-2.497	6.8696	6.4363
100	424.42	437.36	447.47	8.4815	423.58	433.7	443.48	8.1041	-7.701	-3.658	0.9553	3.7088
110	433.61	439.6	443.29	3.7291	424.69	432.92	436.71	4.8383	-18.596	-6.6783	3.1004	7.7426

Device Test: 42.13 UVLO_RISE_VIN(THRESHOLD|RISE/VIN1////90.9/634//0///@UVLO_RISE_VIN)





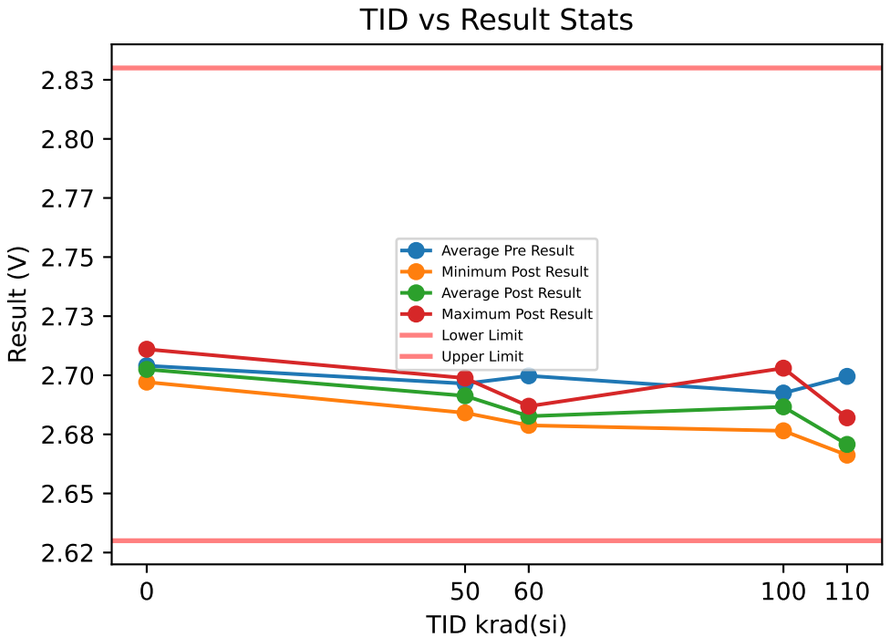
Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

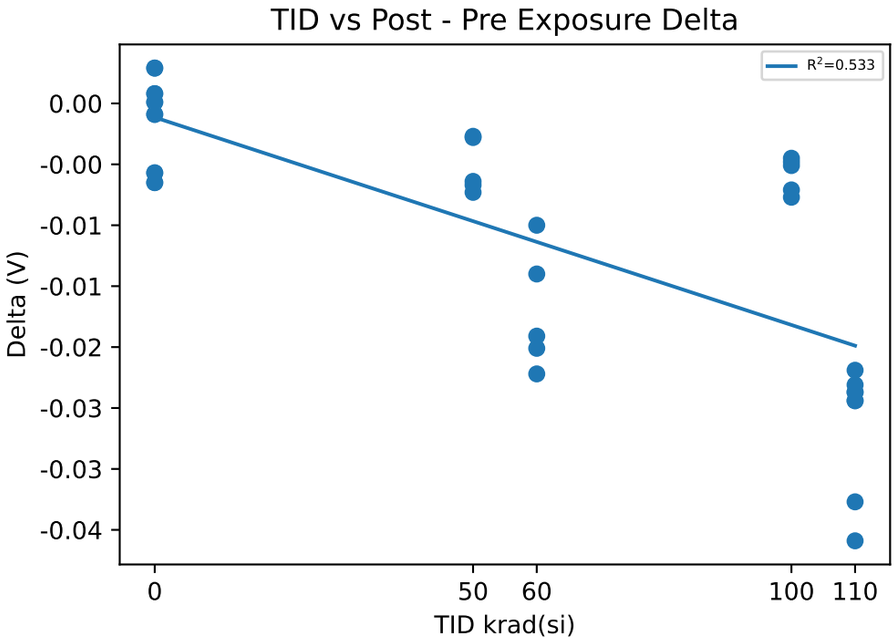
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.6972	-0.0008
2	0	CU2	2.7039	2.704	0.0001
3	0	CU3	2.7102	2.7111	0.0009
11	50	Unbiased-50k	2.7061	2.6988	-0.0073
12	50	Unbiased-50k	2.6904	2.6841	-0.0063
13	50	Unbiased-50k	2.6882	2.6857	-0.0025
14	50	Unbiased-50k	2.6928	2.69	-0.0028
16	50	Unbiased-50k	2.7047	2.698	-0.0067
17	60	Biased-50k	2.6989	2.6789	-0.02
18	60	Biased-50k	2.6969	2.6869	-0.01
19	60	Biased-50k	2.6949	2.681	-0.0139
20	60	Biased-50k	2.702	2.6799	-0.0221
21	60	Biased-50k	2.706	2.6869	-0.0191
24	100	Unbiased-100k	2.687	2.6819	-0.0051
25	100	Unbiased-100k	2.6916	2.6841	-0.0075
26	100	Unbiased-100k	2.681	2.6765	-0.0045
27	100	Unbiased-100k	2.6925	2.6878	-0.0047
28	100	Unbiased-100k	2.7101	2.7031	-0.007
29	110	Biased-100k	2.6953	2.6723	-0.023
30	110	Biased-100k	2.7039	2.682	-0.0219
31	110	Biased-100k	2.7034	2.6709	-0.0325
32	110	Biased-100k	2.7021	2.6662	-0.0359
34	110	Biased-100k	2.6927	2.6684	-0.0243

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061011	2.6972	2.7041	2.7111	0.0069505	-0.0008	6.6667e-05	0.0009	0.00085049
50	2.6882	2.6964	2.7061	0.0083542	2.6841	2.6913	2.6988	0.0068196	-0.0073	-0.00512	-0.0025	0.0022852
60	2.6949	2.6997	2.706	0.004373	2.6789	2.6827	2.6869	0.0038874	-0.0221	-0.01702	-0.01	0.0049505
100	2.681	2.6924	2.7101	0.010875	2.6765	2.6867	2.7031	0.01005	-0.0075	-0.00576	-0.0045	0.0013885
110	2.6927	2.6995	2.7039	0.0051285	2.6662	2.672	2.682	0.0060805	-0.0359	-0.02752	-0.0219	0.0062731

Device Test: 42.14 UVLO_RISE_VIN(THRESHOLD|RISE/VIN2////90.9/634//0///@UVLO_RISE_VIN)





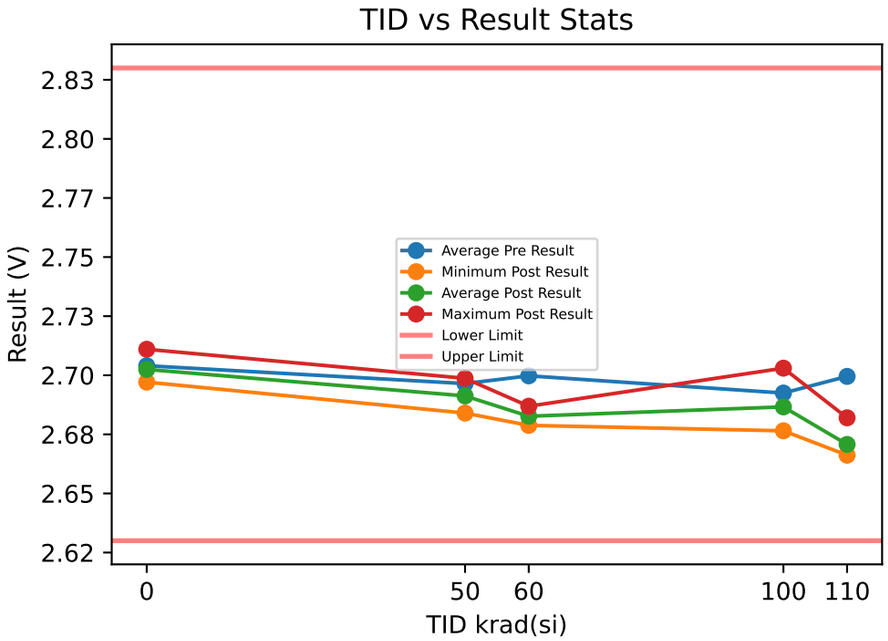
Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

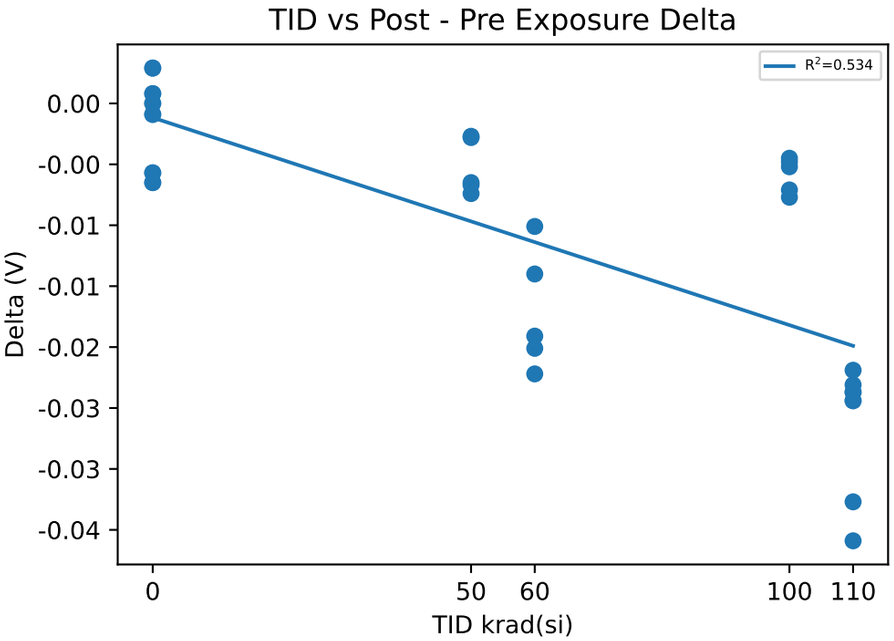
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.6971	-0.0009
2	0	CU2	2.7039	2.704	0.0001
3	0	CU3	2.7102	2.711	0.0008
11	50	Unbiased-50k	2.7061	2.6988	-0.0073
12	50	Unbiased-50k	2.6905	2.6841	-0.0064
13	50	Unbiased-50k	2.6883	2.6856	-0.0027
14	50	Unbiased-50k	2.6928	2.69	-0.0028
16	50	Unbiased-50k	2.7047	2.698	-0.0067
17	60	Biased-50k	2.6989	2.6788	-0.0201
18	60	Biased-50k	2.6969	2.6869	-0.01
19	60	Biased-50k	2.6949	2.6809	-0.014
20	60	Biased-50k	2.7021	2.6799	-0.0222
21	60	Biased-50k	2.706	2.6869	-0.0191
24	100	Unbiased-100k	2.687	2.6819	-0.0051
25	100	Unbiased-100k	2.6917	2.684	-0.0077
26	100	Unbiased-100k	2.681	2.6765	-0.0045
27	100	Unbiased-100k	2.6926	2.6878	-0.0048
28	100	Unbiased-100k	2.7101	2.703	-0.0071
29	110	Biased-100k	2.6954	2.6723	-0.0231
30	110	Biased-100k	2.7039	2.682	-0.0219
31	110	Biased-100k	2.7035	2.6708	-0.0327
32	110	Biased-100k	2.7021	2.6662	-0.0359
34	110	Biased-100k	2.6927	2.6683	-0.0244

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061011	2.6971	2.704	2.711	0.0069501	-0.0009	0	0.0008	0.0008544
50	2.6883	2.6965	2.7061	0.0083116	2.6841	2.6913	2.6988	0.0068403	-0.0073	-0.00518	-0.0027	0.0022421
60	2.6949	2.6998	2.706	0.0043861	2.6788	2.6827	2.6869	0.0039233	-0.0222	-0.01708	-0.01	0.0049756
100	2.681	2.6925	2.7101	0.010873	2.6765	2.6866	2.703	0.010016	-0.0077	-0.00584	-0.0045	0.0014553
110	2.6927	2.6995	2.7039	0.0051276	2.6662	2.6719	2.682	0.0060998	-0.0359	-0.0276	-0.0219	0.0062825

Device Test: 42.15 UVLO_RISE_VIN(THRESHOLD|RISE/VIN3////90.9/634//0///@UVLO_RISE_VIN)





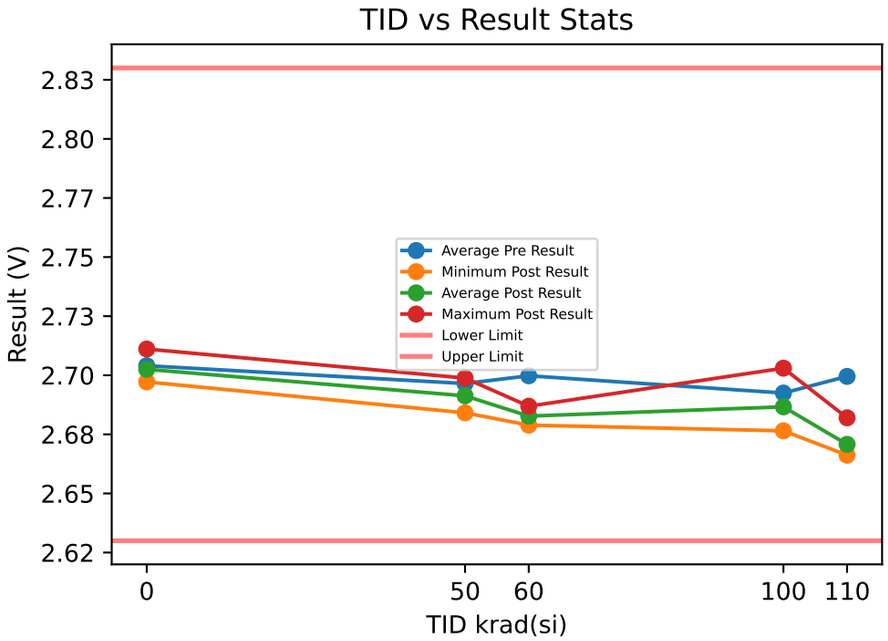
Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

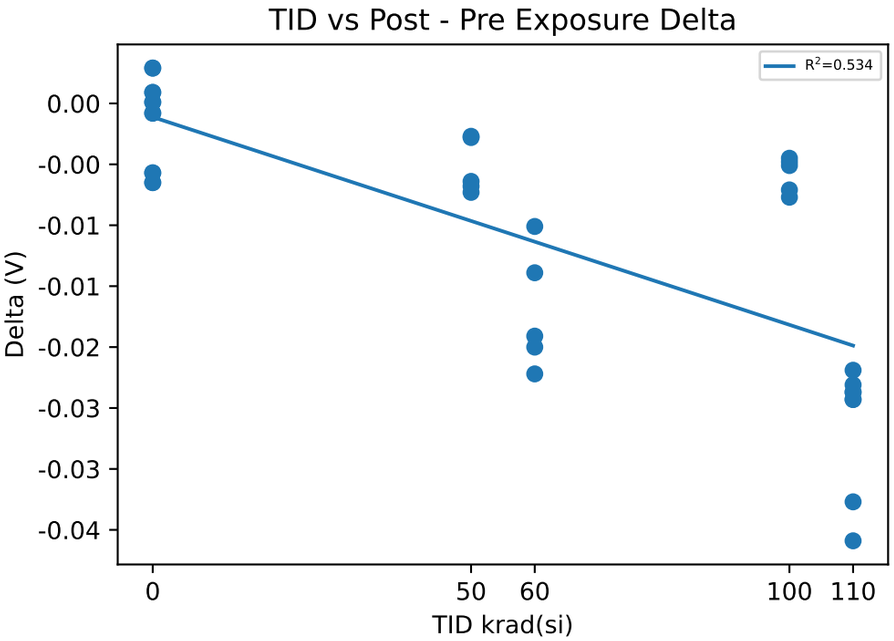
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.6971	-0.0009
2	0	CU2	2.7039	2.7039	0
3	0	CU3	2.7102	2.711	0.0008
11	50	Unbiased-50k	2.7061	2.6987	-0.0074
12	50	Unbiased-50k	2.6905	2.684	-0.0065
13	50	Unbiased-50k	2.6883	2.6856	-0.0027
14	50	Unbiased-50k	2.6928	2.69	-0.0028
16	50	Unbiased-50k	2.7047	2.698	-0.0067
17	60	Biased-50k	2.6989	2.6788	-0.0201
18	60	Biased-50k	2.6969	2.6868	-0.0101
19	60	Biased-50k	2.6949	2.6809	-0.014
20	60	Biased-50k	2.7021	2.6799	-0.0222
21	60	Biased-50k	2.706	2.6869	-0.0191
24	100	Unbiased-100k	2.687	2.6818	-0.0052
25	100	Unbiased-100k	2.6917	2.684	-0.0077
26	100	Unbiased-100k	2.681	2.6765	-0.0045
27	100	Unbiased-100k	2.6926	2.6878	-0.0048
28	100	Unbiased-100k	2.7101	2.703	-0.0071
29	110	Biased-100k	2.6954	2.6723	-0.0231
30	110	Biased-100k	2.7039	2.682	-0.0219
31	110	Biased-100k	2.7035	2.6708	-0.0327
32	110	Biased-100k	2.7021	2.6662	-0.0359
34	110	Biased-100k	2.6927	2.6683	-0.0244

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061011	2.6971	2.704	2.711	0.0069505	-0.0009	-3.3333e-05	0.0008	0.00085049
50	2.6883	2.6965	2.7061	0.0083116	2.684	2.6913	2.6987	0.0068394	-0.0074	-0.00522	-0.0027	0.0022797
60	2.6949	2.6998	2.706	0.0043861	2.6788	2.6827	2.6869	0.0038965	-0.0222	-0.0171	-0.0101	0.0049401
100	2.681	2.6925	2.7101	0.010873	2.6765	2.6866	2.703	0.010028	-0.0077	-0.00586	-0.0045	0.0014433
110	2.6927	2.6995	2.7039	0.0051276	2.6662	2.6719	2.682	0.0060998	-0.0359	-0.0276	-0.0219	0.0062825

Device Test: 42.16 UVLO_RISE_VIN(THRESHOLD|RISE/VIN4/////90.9/634//0///@UVLO_RISE_VIN)





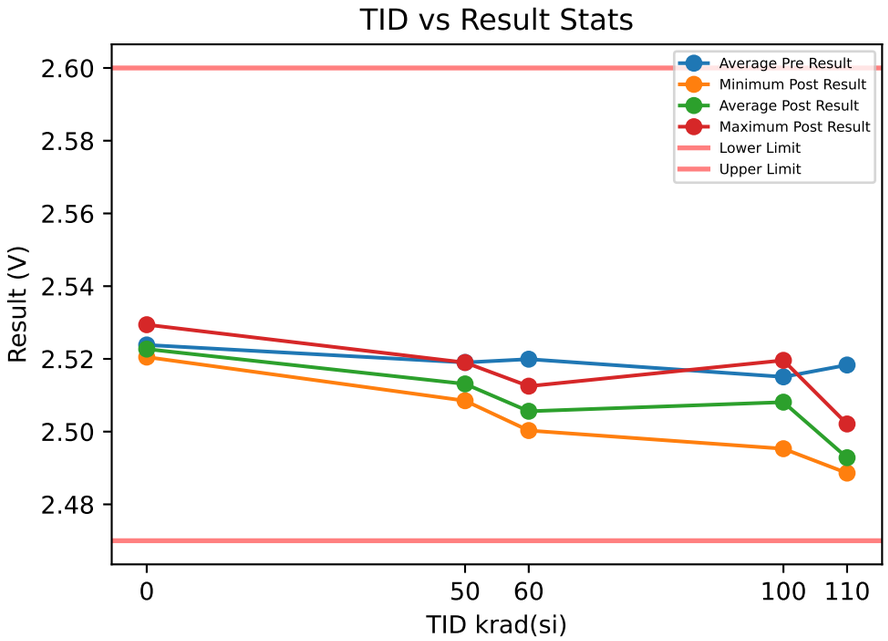
Test Results (Lower Limit = 2.63, Upper Limit = 2.83 (V))

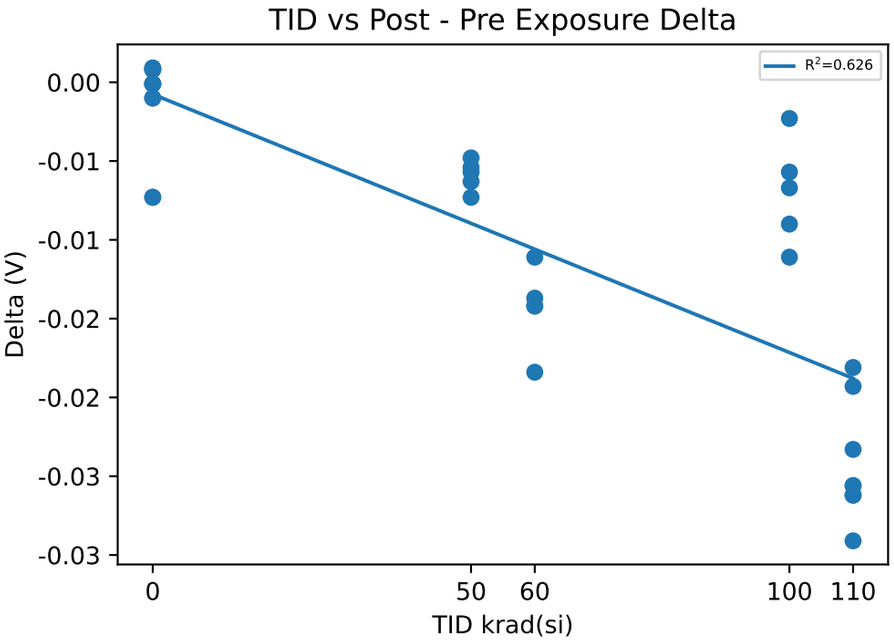
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.698	2.6972	-0.0008
2	0	CU2	2.7039	2.704	0.0001
3	0	CU3	2.7102	2.7111	0.0009
11	50	Unbiased-50k	2.7061	2.6988	-0.0073
12	50	Unbiased-50k	2.6905	2.6841	-0.0064
13	50	Unbiased-50k	2.6883	2.6856	-0.0027
14	50	Unbiased-50k	2.6928	2.69	-0.0028
16	50	Unbiased-50k	2.7048	2.698	-0.0068
17	60	Biased-50k	2.6989	2.6789	-0.02
18	60	Biased-50k	2.697	2.6869	-0.0101
19	60	Biased-50k	2.6949	2.681	-0.0139
20	60	Biased-50k	2.7021	2.6799	-0.0222
21	60	Biased-50k	2.706	2.6869	-0.0191
24	100	Unbiased-100k	2.687	2.6819	-0.0051
25	100	Unbiased-100k	2.6917	2.684	-0.0077
26	100	Unbiased-100k	2.681	2.6765	-0.0045
27	100	Unbiased-100k	2.6926	2.6878	-0.0048
28	100	Unbiased-100k	2.7101	2.703	-0.0071
29	110	Biased-100k	2.6954	2.6723	-0.0231
30	110	Biased-100k	2.7039	2.682	-0.0219
31	110	Biased-100k	2.7035	2.6708	-0.0327
32	110	Biased-100k	2.7021	2.6662	-0.0359
34	110	Biased-100k	2.6927	2.6684	-0.0243

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.698	2.704	2.7102	0.0061011	2.6972	2.7041	2.7111	0.0069505	-0.0008	6.6667e-05	0.0009	0.00085049
50	2.6883	2.6965	2.7061	0.0083364	2.6841	2.6913	2.6988	0.0068403	-0.0073	-0.0052	-0.0027	0.0022594
60	2.6949	2.6998	2.706	0.00437	2.6789	2.6827	2.6869	0.0038874	-0.0222	-0.01706	-0.0101	0.004941
100	2.681	2.6925	2.7101	0.010873	2.6765	2.6866	2.703	0.010016	-0.0077	-0.00584	-0.0045	0.0014553
110	2.6927	2.6995	2.7039	0.0051276	2.6662	2.6719	2.682	0.0060851	-0.0359	-0.02758	-0.0219	0.0062954

Device Test: 42.17 UVLO_FALL_VIN(THRESHOLD|FALL/VIN1////90.9/634//0///@UVLO_FALL_VIN)





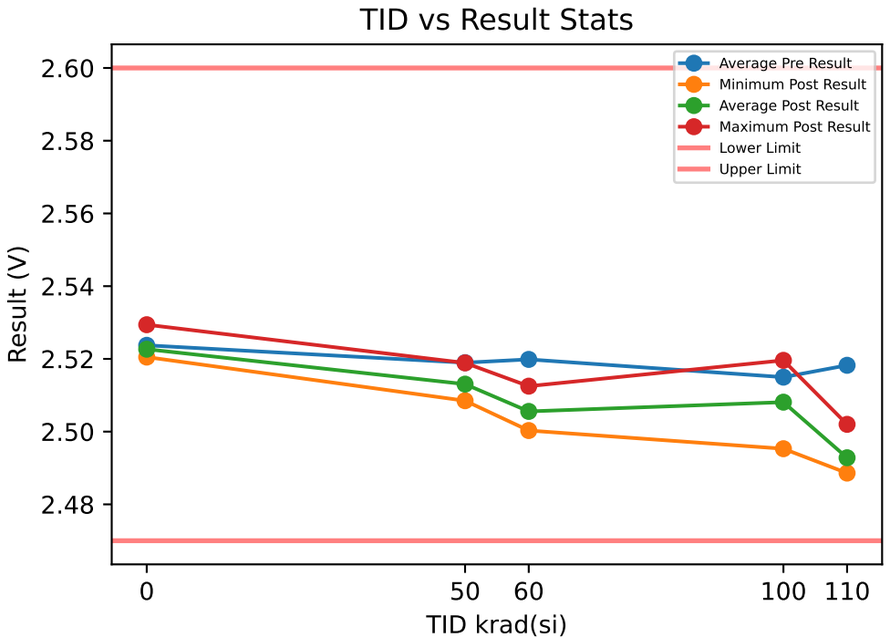
Test Results (Lower Limit = 2.47, Upper Limit = 2.6 (V))

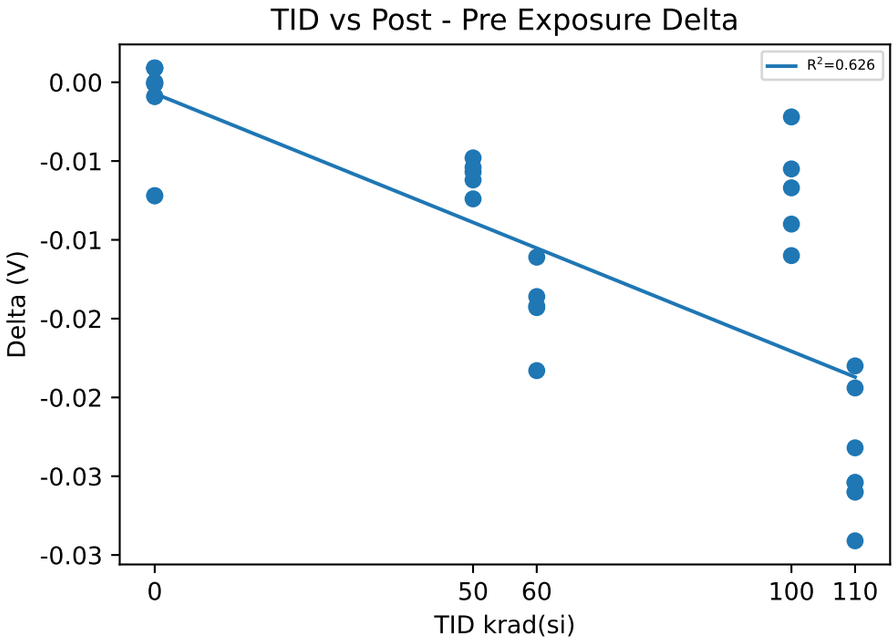
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5215	2.5205	-0.001
2	0	CU2	2.5214	2.5213	-0.0001
3	0	CU3	2.5286	2.5294	0.0008
11	50	Unbiased-50k	2.5263	2.519	-0.0073
12	50	Unbiased-50k	2.5149	2.5086	-0.0063
13	50	Unbiased-50k	2.5133	2.5085	-0.0048
14	50	Unbiased-50k	2.5182	2.5125	-0.0057
16	50	Unbiased-50k	2.5224	2.517	-0.0054
17	60	Biased-50k	2.5195	2.5053	-0.0142
18	60	Biased-50k	2.5195	2.5053	-0.0142
19	60	Biased-50k	2.5183	2.5046	-0.0137
20	60	Biased-50k	2.5187	2.5003	-0.0184
21	60	Biased-50k	2.5236	2.5125	-0.0111
24	100	Unbiased-100k	2.5156	2.5066	-0.009
25	100	Unbiased-100k	2.5114	2.5057	-0.0057
26	100	Unbiased-100k	2.5064	2.4953	-0.0111
27	100	Unbiased-100k	2.5156	2.5133	-0.0023
28	100	Unbiased-100k	2.5263	2.5196	-0.0067
29	110	Biased-100k	2.5144	2.4963	-0.0181
30	110	Biased-100k	2.5214	2.5021	-0.0193
31	110	Biased-100k	2.5196	2.4963	-0.0233
32	110	Biased-100k	2.5214	2.4923	-0.0291
34	110	Biased-100k	2.5148	2.4886	-0.0262

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5214	2.5238	2.5286	0.0041284	2.5205	2.5237	2.5294	0.0049238	-0.001	-0.0001	0.0008	0.0009
50	2.5133	2.519	2.5263	0.005357	2.5085	2.5131	2.519	0.0047903	-0.0073	-0.0059	-0.0048	0.00095131
60	2.5183	2.5199	2.5236	0.0021218	2.5003	2.5056	2.5125	0.0043841	-0.0184	-0.01432	-0.0111	0.0026186
100	2.5064	2.5151	2.5263	0.0073368	2.4953	2.5081	2.5196	0.0090986	-0.0111	-0.00696	-0.0023	0.0033419
110	2.5144	2.5183	2.5214	0.0034774	2.4886	2.4951	2.5021	0.005049	-0.0291	-0.0232	-0.0181	0.0046109

Device Test: 42.18 UVLO_FALL_VIN(THRESHOLD|FALL/VIN2////90.9/634//0///@UVLO_FALL_VIN)





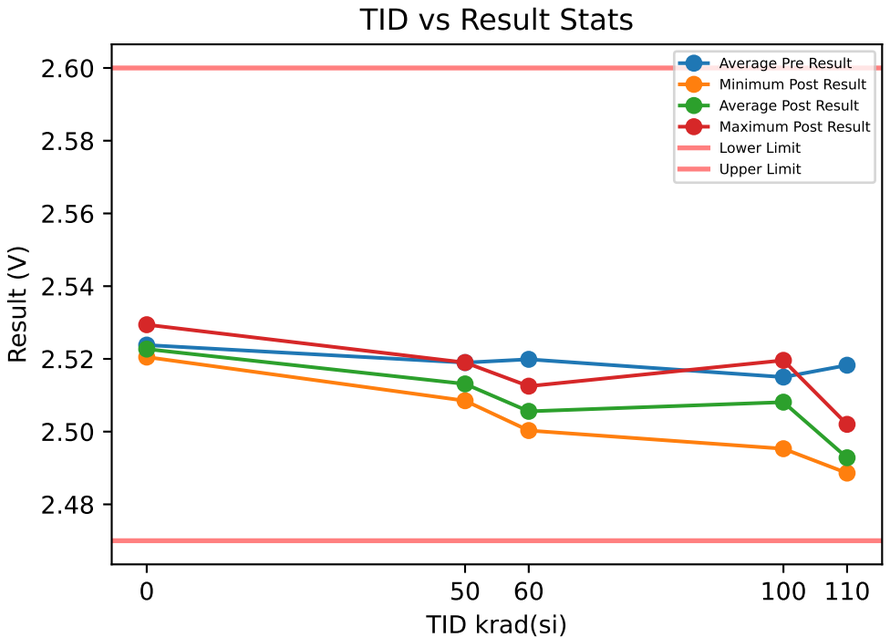
Test Results (Lower Limit = 2.47, Upper Limit = 2.6 (V))

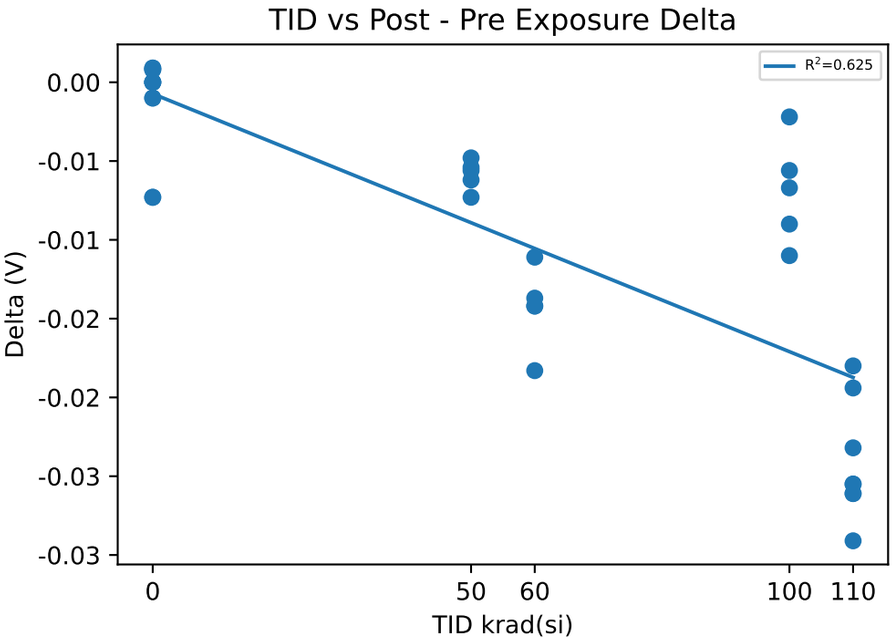
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5214	2.5205	-0.0009
2	0	CU2	2.5213	2.5213	0
3	0	CU3	2.5285	2.5294	0.0009
11	50	Unbiased-50k	2.5263	2.5189	-0.0074
12	50	Unbiased-50k	2.5147	2.5085	-0.0062
13	50	Unbiased-50k	2.5133	2.5085	-0.0048
14	50	Unbiased-50k	2.5181	2.5124	-0.0057
16	50	Unbiased-50k	2.5224	2.517	-0.0054
17	60	Biased-50k	2.5194	2.5052	-0.0142
18	60	Biased-50k	2.5195	2.5052	-0.0143
19	60	Biased-50k	2.5182	2.5046	-0.0136
20	60	Biased-50k	2.5186	2.5003	-0.0183
21	60	Biased-50k	2.5236	2.5125	-0.0111
24	100	Unbiased-100k	2.5156	2.5066	-0.009
25	100	Unbiased-100k	2.5112	2.5057	-0.0055
26	100	Unbiased-100k	2.5063	2.4953	-0.011
27	100	Unbiased-100k	2.5155	2.5133	-0.0022
28	100	Unbiased-100k	2.5263	2.5196	-0.0067
29	110	Biased-100k	2.5143	2.4963	-0.018
30	110	Biased-100k	2.5214	2.502	-0.0194
31	110	Biased-100k	2.5195	2.4963	-0.0232
32	110	Biased-100k	2.5214	2.4923	-0.0291
34	110	Biased-100k	2.5146	2.4886	-0.026

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5213	2.5237	2.5285	0.0041284	2.5205	2.5237	2.5294	0.0049238	-0.0009	0	0.0009	0.0009
50	2.5133	2.519	2.5263	0.0053998	2.5085	2.5131	2.5189	0.0047868	-0.0074	-0.0059	-0.0048	0.0009798
60	2.5182	2.5199	2.5236	0.0021606	2.5003	2.5056	2.5125	0.0043878	-0.0183	-0.0143	-0.0111	0.0025855
100	2.5063	2.515	2.5263	0.0073897	2.4953	2.5081	2.5196	0.0090986	-0.011	-0.00688	-0.0022	0.0033656
110	2.5143	2.5182	2.5214	0.0035473	2.4886	2.4951	2.502	0.0050145	-0.0291	-0.02314	-0.018	0.0045856

Device Test: 42.19 UVLO_FALL_VIN(THRESHOLD|FALL/VIN3////90.9/634//0///@UVLO_FALL_VIN)





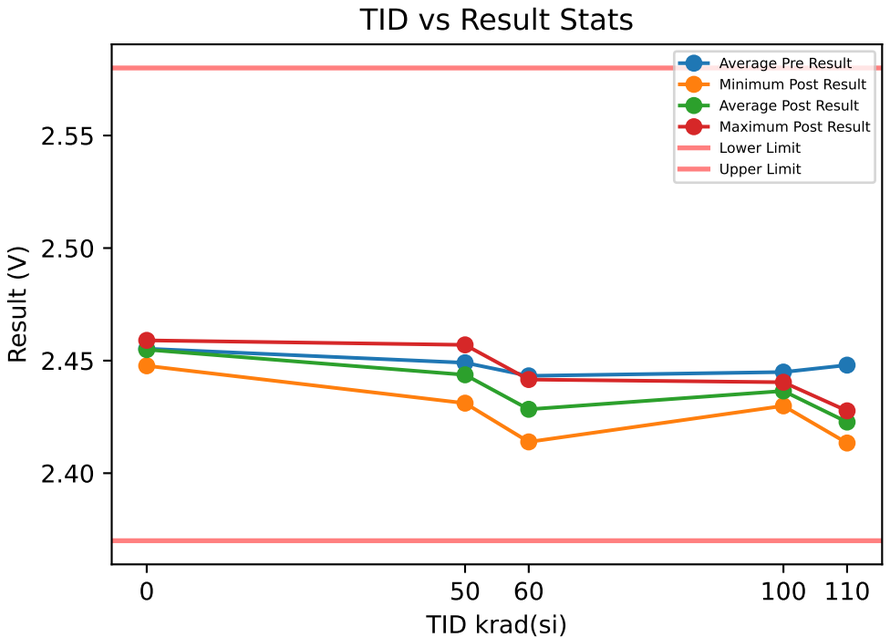
Test Results (Lower Limit = 2.47, Upper Limit = 2.6 (V))

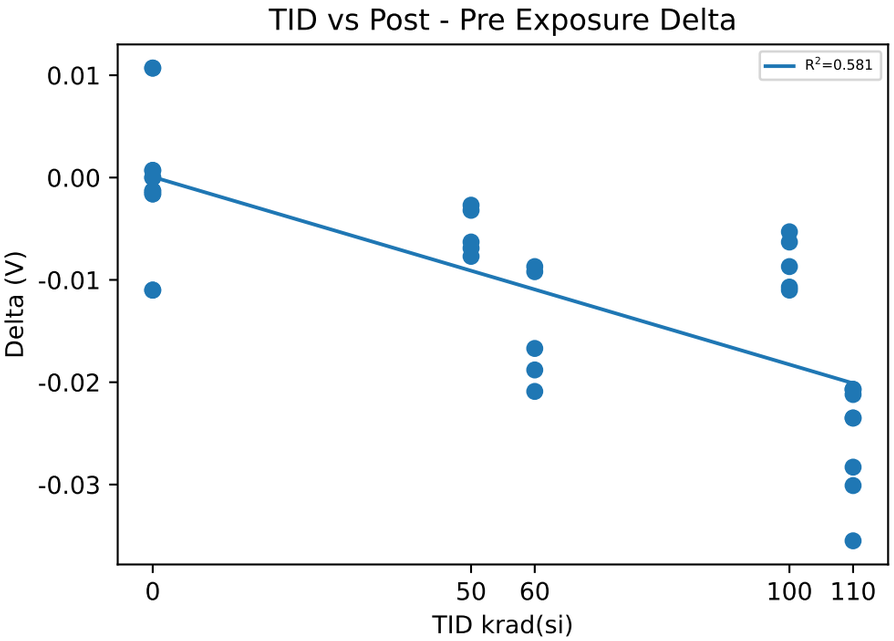
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5215	2.5205	-0.001
2	0	CU2	2.5213	2.5213	0
3	0	CU3	2.5286	2.5294	0.0008
11	50	Unbiased-50k	2.5263	2.519	-0.0073
12	50	Unbiased-50k	2.5148	2.5086	-0.0062
13	50	Unbiased-50k	2.5133	2.5085	-0.0048
14	50	Unbiased-50k	2.5181	2.5125	-0.0056
16	50	Unbiased-50k	2.5224	2.517	-0.0054
17	60	Biased-50k	2.5194	2.5052	-0.0142
18	60	Biased-50k	2.5195	2.5053	-0.0142
19	60	Biased-50k	2.5183	2.5046	-0.0137
20	60	Biased-50k	2.5186	2.5003	-0.0183
21	60	Biased-50k	2.5236	2.5125	-0.0111
24	100	Unbiased-100k	2.5156	2.5066	-0.009
25	100	Unbiased-100k	2.5113	2.5057	-0.0056
26	100	Unbiased-100k	2.5063	2.4953	-0.011
27	100	Unbiased-100k	2.5155	2.5133	-0.0022
28	100	Unbiased-100k	2.5263	2.5196	-0.0067
29	110	Biased-100k	2.5143	2.4963	-0.018
30	110	Biased-100k	2.5214	2.502	-0.0194
31	110	Biased-100k	2.5195	2.4963	-0.0232
32	110	Biased-100k	2.5214	2.4923	-0.0291
34	110	Biased-100k	2.5147	2.4886	-0.0261

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5213	2.5238	2.5286	0.0041581	2.5205	2.5237	2.5294	0.0049238	-0.001	-6.6667e-05	0.0008	0.00090185
50	2.5133	2.519	2.5263	0.0053802	2.5085	2.5131	2.519	0.0047903	-0.0073	-0.00586	-0.0048	0.00094763
60	2.5183	2.5199	2.5236	0.0021417	2.5003	2.5056	2.5125	0.004386	-0.0183	-0.0143	-0.0111	0.0025797
100	2.5063	2.515	2.5263	0.007377	2.4953	2.5081	2.5196	0.0090986	-0.011	-0.0069	-0.0022	0.0033556
110	2.5143	2.5183	2.5214	0.0035218	2.4886	2.4951	2.502	0.0050145	-0.0291	-0.02316	-0.018	0.0046014

Device Test: 42.2 UVLO_RISE_PVIN(THRESHOLD|RISE/PVIN2////90.9/634//0///@UVLO_RISE_PVIN)





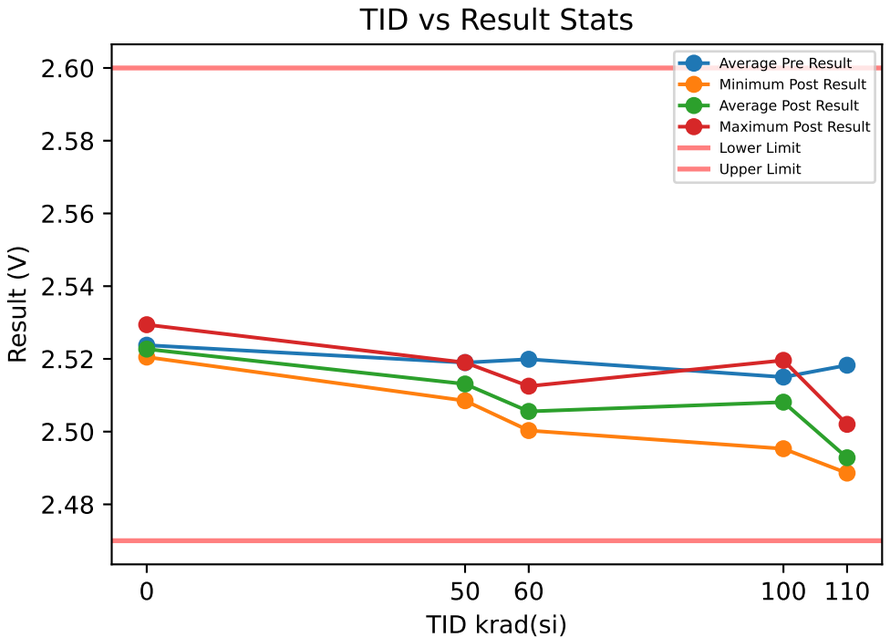
Test Results (Lower Limit = 2.37, Upper Limit = 2.58 (V))

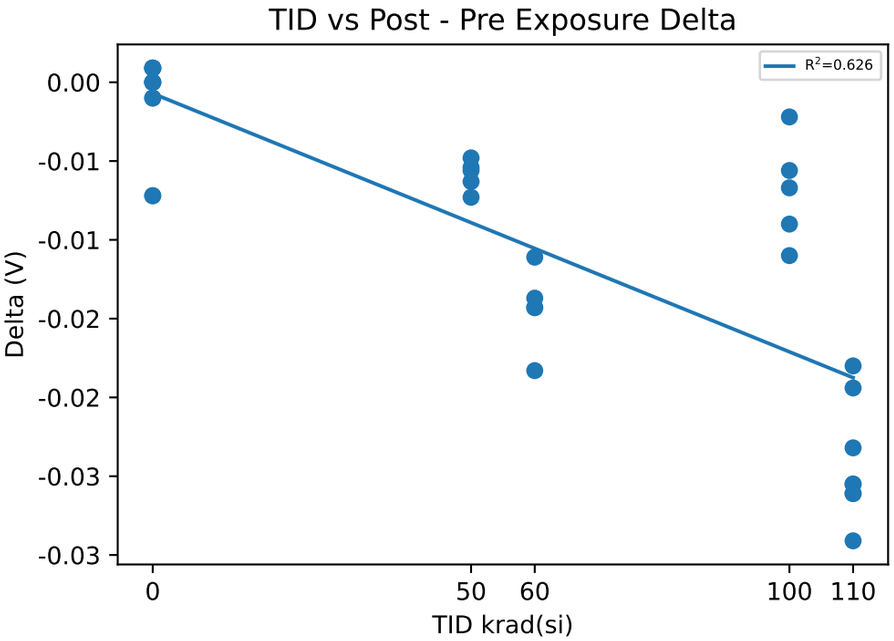
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4599	2.4583	-0.0016
2	0	CU2	2.447	2.4477	0.0007
3	0	CU3	2.459	2.459	0
11	50	Unbiased-50k	2.4602	2.457	-0.0032
12	50	Unbiased-50k	2.4446	2.4419	-0.0027
13	50	Unbiased-50k	2.4477	2.4408	-0.0069
14	50	Unbiased-50k	2.4388	2.4311	-0.0077
16	50	Unbiased-50k	2.454	2.4477	-0.0063
17	60	Biased-50k	2.4399	2.4307	-0.0092
18	60	Biased-50k	2.4484	2.4296	-0.0188
19	60	Biased-50k	2.4348	2.4139	-0.0209
20	60	Biased-50k	2.4428	2.4261	-0.0167
21	60	Biased-50k	2.4503	2.4416	-0.0087
24	100	Unbiased-100k	2.4489	2.4402	-0.0087
25	100	Unbiased-100k	2.4467	2.4404	-0.0063
26	100	Unbiased-100k	2.4352	2.4299	-0.0053
27	100	Unbiased-100k	2.4473	2.4366	-0.0107
28	100	Unbiased-100k	2.4465	2.4355	-0.011
29	110	Biased-100k	2.4487	2.4204	-0.0283
30	110	Biased-100k	2.4455	2.4243	-0.0212
31	110	Biased-100k	2.4489	2.4134	-0.0355
32	110	Biased-100k	2.4485	2.4184	-0.0301
34	110	Biased-100k	2.4484	2.4249	-0.0235

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.447	2.4553	2.4599	0.0072021	2.4477	2.455	2.459	0.0063317	-0.0016	-0.0003	0.0007	0.001179
50	2.4388	2.4491	2.4602	0.0082993	2.4311	2.4437	2.457	0.0095302	-0.0077	-0.00536	-0.0027	0.0022623
60	2.4348	2.4432	2.4503	0.0063058	2.4139	2.4284	2.4416	0.0099563	-0.0209	-0.01486	-0.0087	0.0055985
100	2.4352	2.4449	2.4489	0.0055147	2.4299	2.4365	2.4404	0.0042857	-0.011	-0.0084	-0.0053	0.0025573
110	2.4455	2.448	2.4489	0.0014107	2.4134	2.4203	2.4249	0.0047007	-0.0355	-0.02772	-0.0212	0.0056313

Device Test: 42.20 UVLO_FALL_VIN(THRESHOLD|FALL/VIN4/////90.9/634//0///@UVLO_FALL_VIN)





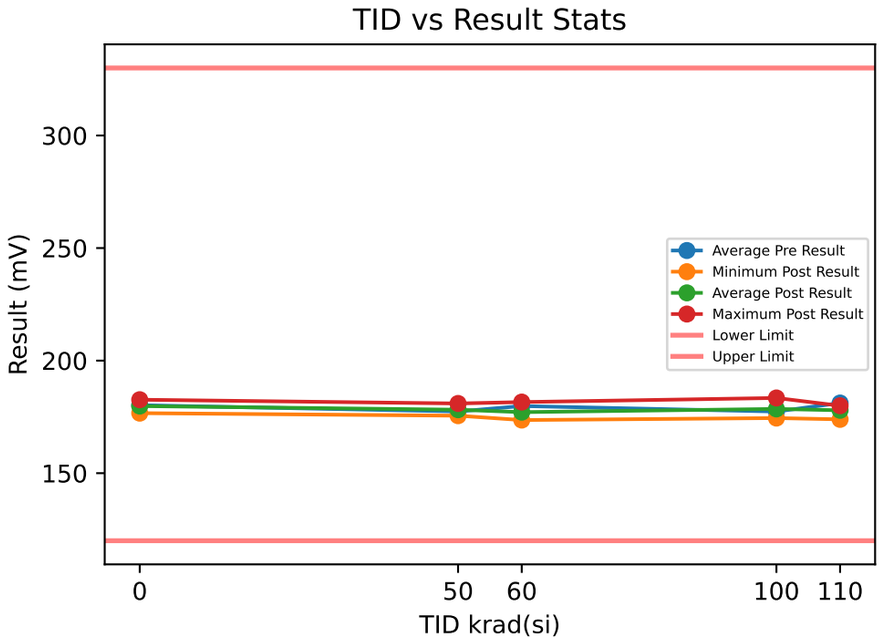
Test Results (Lower Limit = 2.47, Upper Limit = 2.6 (V))

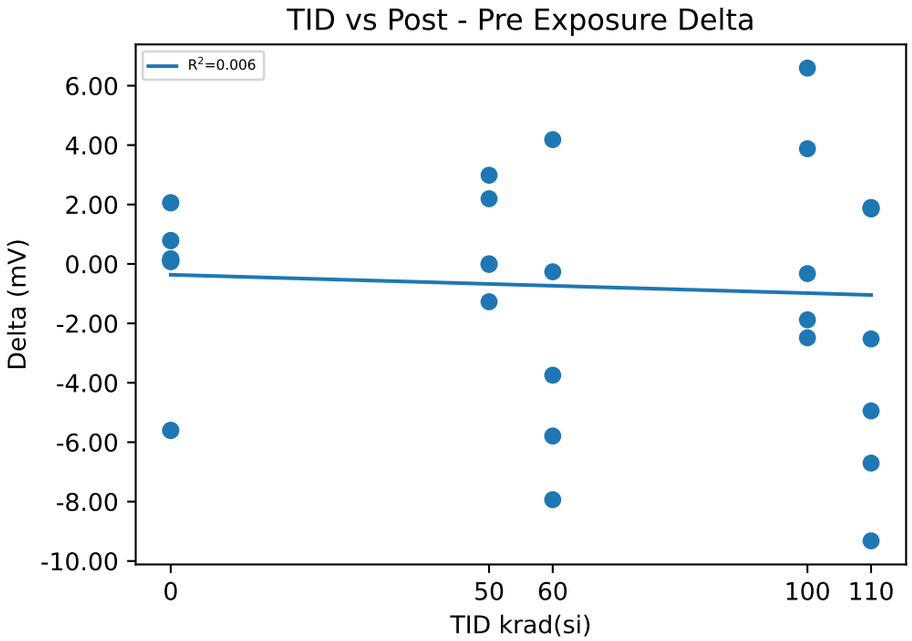
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.5215	2.5205	-0.001
2	0	CU2	2.5213	2.5213	0
3	0	CU3	2.5285	2.5294	0.0009
11	50	Unbiased-50k	2.5263	2.519	-0.0073
12	50	Unbiased-50k	2.5148	2.5085	-0.0063
13	50	Unbiased-50k	2.5133	2.5085	-0.0048
14	50	Unbiased-50k	2.5181	2.5125	-0.0056
16	50	Unbiased-50k	2.5224	2.517	-0.0054
17	60	Biased-50k	2.5195	2.5052	-0.0143
18	60	Biased-50k	2.5195	2.5052	-0.0143
19	60	Biased-50k	2.5183	2.5046	-0.0137
20	60	Biased-50k	2.5186	2.5003	-0.0183
21	60	Biased-50k	2.5236	2.5125	-0.0111
24	100	Unbiased-100k	2.5156	2.5066	-0.009
25	100	Unbiased-100k	2.5113	2.5057	-0.0056
26	100	Unbiased-100k	2.5063	2.4953	-0.011
27	100	Unbiased-100k	2.5155	2.5133	-0.0022
28	100	Unbiased-100k	2.5263	2.5196	-0.0067
29	110	Biased-100k	2.5143	2.4963	-0.018
30	110	Biased-100k	2.5214	2.502	-0.0194
31	110	Biased-100k	2.5195	2.4963	-0.0232
32	110	Biased-100k	2.5214	2.4923	-0.0291
34	110	Biased-100k	2.5147	2.4886	-0.0261

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5213	2.5238	2.5285	0.0041004	2.5205	2.5237	2.5294	0.0049238	-0.001	-3.3333e-05	0.0009	0.00095044
50	2.5133	2.519	2.5263	0.0053802	2.5085	2.5131	2.519	0.004814	-0.0073	-0.00588	-0.0048	0.0009576
60	2.5183	2.5199	2.5236	0.0021366	2.5003	2.5056	2.5125	0.0043878	-0.0183	-0.01434	-0.0111	0.0025784
100	2.5063	2.515	2.5263	0.007377	2.4953	2.5081	2.5196	0.0090986	-0.011	-0.0069	-0.0022	0.0033556
110	2.5143	2.5183	2.5214	0.0035218	2.4886	2.4951	2.502	0.0050145	-0.0291	-0.02316	-0.018	0.0046014

Device Test: 42.21 UVLO_HYST_VIN(THRESHOLD|HYST/VIN1/////90.9/634//0///@UVLO_HYST_VIN)





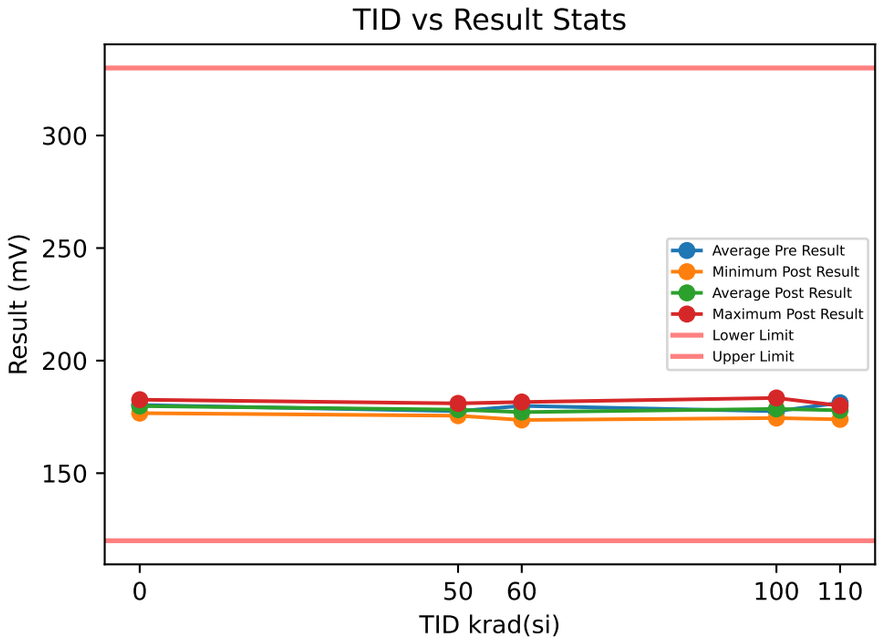
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

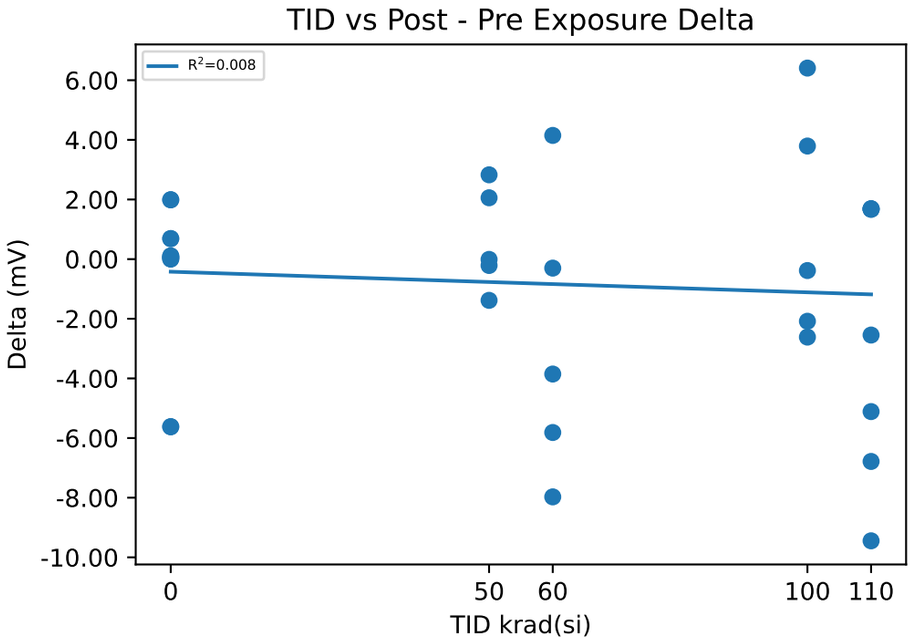
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.5	176.67	0.1708
2	0	CU2	182.54	182.64	0.0986
3	0	CU3	181.6	181.68	0.0817
11	50	Unbiased-50k	179.76	179.76	0.0058
12	50	Unbiased-50k	175.56	175.54	-0.0155
13	50	Unbiased-50k	174.94	177.13	2.1951
14	50	Unbiased-50k	174.57	177.56	2.9857
16	50	Unbiased-50k	182.24	180.97	-1.272
17	60	Biased-50k	179.4	173.6	-5.7919
18	60	Biased-50k	177.4	181.59	4.1843
19	60	Biased-50k	176.61	176.35	-0.265
20	60	Biased-50k	183.34	179.6	-3.745
21	60	Biased-50k	182.37	174.44	-7.9351
24	100	Unbiased-100k	171.39	175.27	3.8779
25	100	Unbiased-100k	180.24	178.36	-1.8813
26	100	Unbiased-100k	174.59	181.19	6.5929
27	100	Unbiased-100k	176.97	174.48	-2.4856
28	100	Unbiased-100k	183.74	183.41	-0.3255
29	110	Biased-100k	180.97	176.02	-4.9468
30	110	Biased-100k	182.49	179.96	-2.5244
31	110	Biased-100k	183.85	174.53	-9.3198
32	110	Biased-100k	180.62	173.92	-6.7032
34	110	Biased-100k	177.9	179.79	1.896

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.5	180.21	182.54	3.2486	176.67	180.33	182.64	3.2038	0.0817	0.11703	0.1708	0.047324
50	174.57	177.41	182.24	3.4057	175.54	178.19	180.97	2.1625	-1.272	0.77982	2.9857	1.7543
60	176.61	179.83	183.34	2.9667	173.6	177.11	181.59	3.4009	-7.9351	-2.7105	4.1843	4.7797
100	171.39	177.39	183.74	4.8053	174.48	178.54	183.41	3.8045	-2.4856	1.1557	6.5929	3.9259
110	177.9	181.16	183.85	2.2343	173.92	176.84	179.96	2.8731	-9.3198	-4.3196	1.896	4.2701

Device Test: 42.22 UVLO_HYST_VIN(THRESHOLD|HYST/VIN2/////90.9/634//0///@UVLO_HYST_VIN)





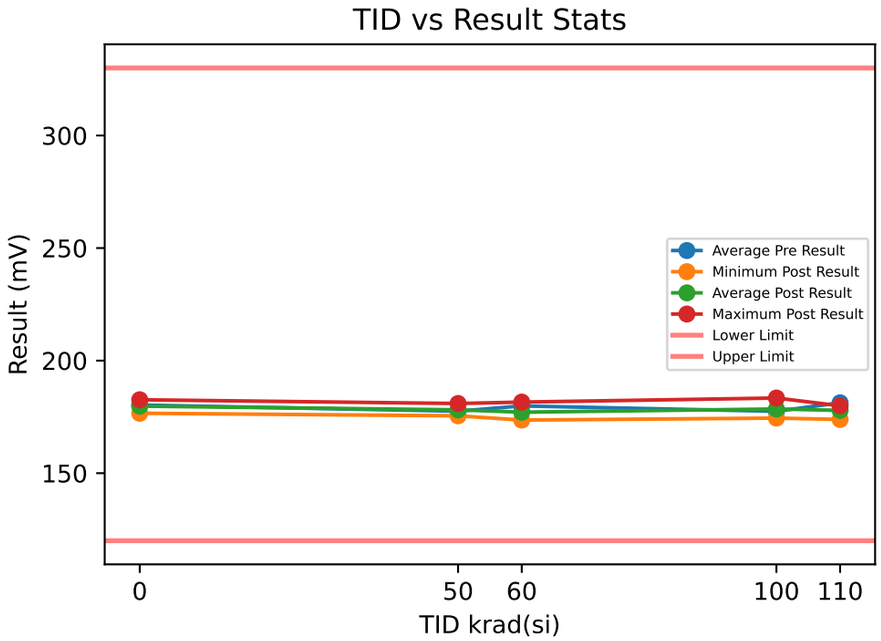
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

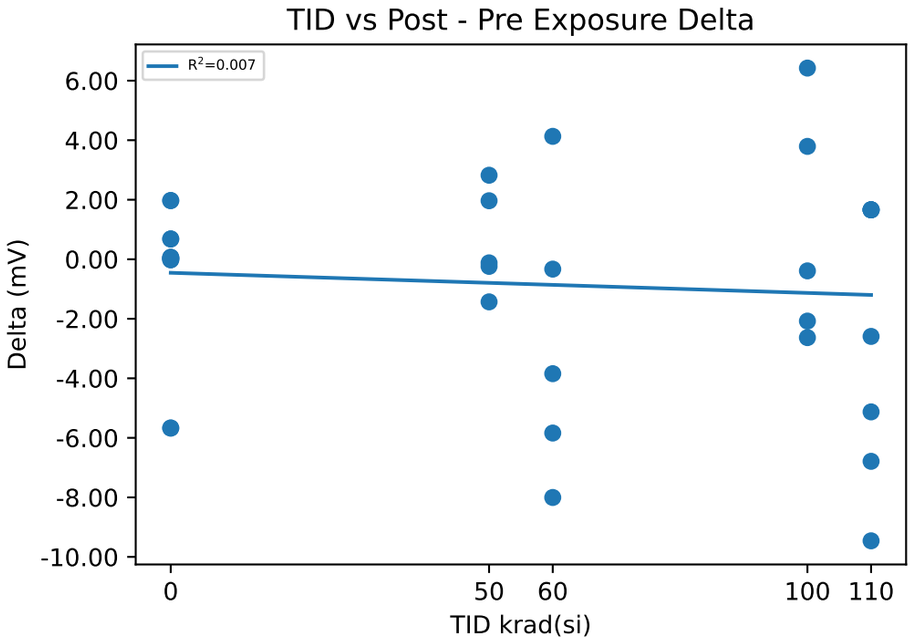
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.57	176.67	0.1057
2	0	CU2	182.59	182.64	0.0559
3	0	CU3	181.69	181.7	0.0046
11	50	Unbiased-50k	179.82	179.81	-0.0092
12	50	Unbiased-50k	175.75	175.53	-0.2127
13	50	Unbiased-50k	175.09	177.15	2.0575
14	50	Unbiased-50k	174.74	177.57	2.8275
16	50	Unbiased-50k	182.39	181	-1.3825
17	60	Biased-50k	179.44	173.63	-5.8141
18	60	Biased-50k	177.46	181.61	4.1485
19	60	Biased-50k	176.68	176.37	-0.3015
20	60	Biased-50k	183.45	179.6	-3.8533
21	60	Biased-50k	182.43	174.45	-7.9724
24	100	Unbiased-100k	171.48	175.27	3.7926
25	100	Unbiased-100k	180.46	178.37	-2.0833
26	100	Unbiased-100k	174.78	181.18	6.4069
27	100	Unbiased-100k	177.1	174.49	-2.6146
28	100	Unbiased-100k	183.79	183.41	-0.3829
29	110	Biased-100k	181.13	176.01	-5.1128
30	110	Biased-100k	182.54	179.99	-2.5459
31	110	Biased-100k	183.97	174.53	-9.4464
32	110	Biased-100k	180.69	173.9	-6.7847
34	110	Biased-100k	178.08	179.77	1.6897

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.57	180.28	182.59	3.2488	176.67	180.34	182.64	3.2094	0.0046	0.0554	0.1057	0.050552
50	174.74	177.56	182.39	3.3822	175.53	178.21	181	2.1839	-1.3825	0.65612	2.8275	1.7344
60	176.68	179.89	183.45	2.9826	173.63	177.13	181.61	3.3965	-7.9724	-2.7586	4.1485	4.7818
100	171.48	177.52	183.79	4.8014	174.49	178.54	183.41	3.8033	-2.6146	1.0237	6.4069	3.9216
110	178.08	181.28	183.97	2.2041	173.9	176.84	179.99	2.8808	-9.4464	-4.44	1.6897	4.2478

Device Test: 42.23 UVLO_HYST_VIN(THRESHOLD|HYST/VIN3/////90.9/634//0///@UVLO_HYST_VIN)





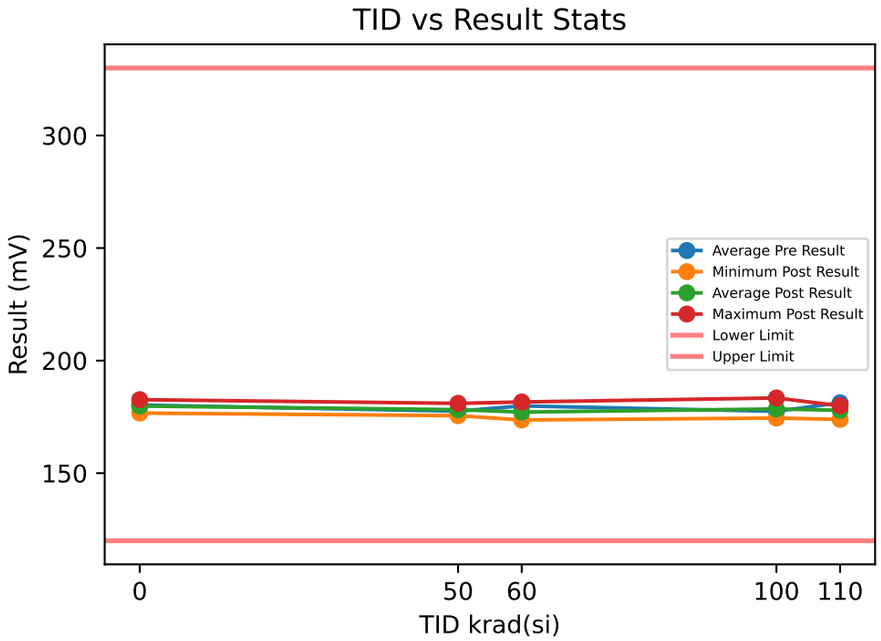
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

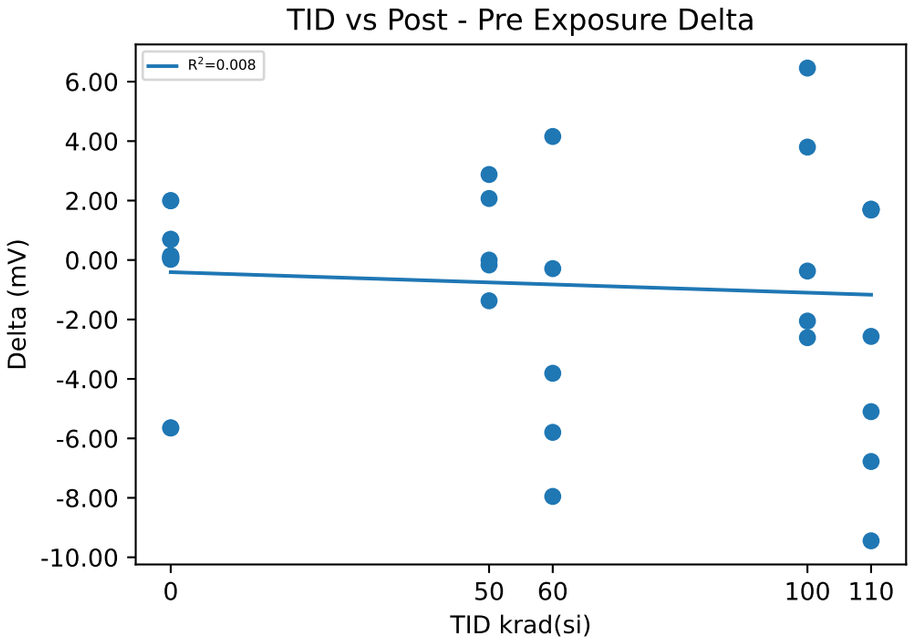
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.55	176.62	0.0651
2	0	CU2	182.58	182.61	0.0302
3	0	CU3	181.68	181.67	-0.0168
11	50	Unbiased-50k	179.81	179.69	-0.1212
12	50	Unbiased-50k	175.73	175.49	-0.2389
13	50	Unbiased-50k	175.07	177.04	1.966
14	50	Unbiased-50k	174.71	177.53	2.8231
16	50	Unbiased-50k	182.38	180.95	-1.4313
17	60	Biased-50k	179.43	173.59	-5.8389
18	60	Biased-50k	177.45	181.58	4.1295
19	60	Biased-50k	176.66	176.33	-0.3312
20	60	Biased-50k	183.42	179.57	-3.8442
21	60	Biased-50k	182.41	174.41	-8.0037
24	100	Unbiased-100k	171.45	175.25	3.7923
25	100	Unbiased-100k	180.42	178.34	-2.0773
26	100	Unbiased-100k	174.72	181.15	6.4233
27	100	Unbiased-100k	177.1	174.47	-2.6328
28	100	Unbiased-100k	183.78	183.39	-0.3905
29	110	Biased-100k	181.11	175.98	-5.1279
30	110	Biased-100k	182.53	179.94	-2.5922
31	110	Biased-100k	183.96	174.5	-9.4599
32	110	Biased-100k	180.67	173.88	-6.7889
34	110	Biased-100k	178.06	179.72	1.6612

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.55	180.27	182.58	3.2518	176.62	180.3	182.61	3.2218	-0.0168	0.026167	0.0651	0.041099
50	174.71	177.54	182.38	3.3909	175.49	178.14	180.95	2.1747	-1.4313	0.59954	2.8231	1.7434
60	176.66	179.87	183.42	2.9747	173.59	177.1	181.58	3.4027	-8.0037	-2.7777	4.1295	4.7832
100	171.45	177.49	183.78	4.8045	174.47	178.52	183.39	3.8002	-2.6328	1.023	6.4233	3.9309
110	178.06	181.26	183.96	2.2065	173.88	176.8	179.94	2.8681	-9.4599	-4.4615	1.6612	4.2375

Device Test: 42.24 UVLO_HYST_VIN(THRESHOLD|HYST/VIN4/////90.9/634//0///@UVLO_HYST_VIN)





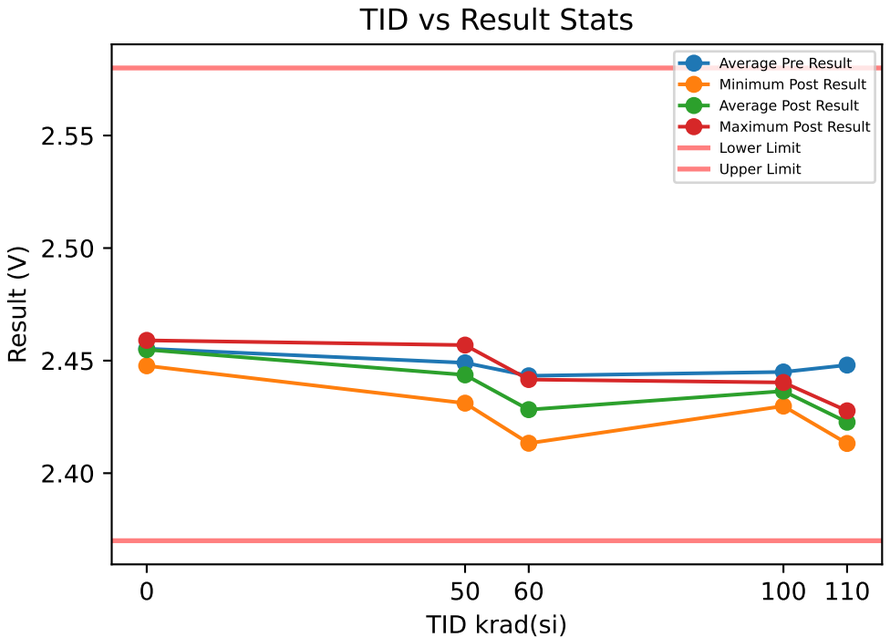
Test Results (Lower Limit = 120.0, Upper Limit = 330.0 (mV))

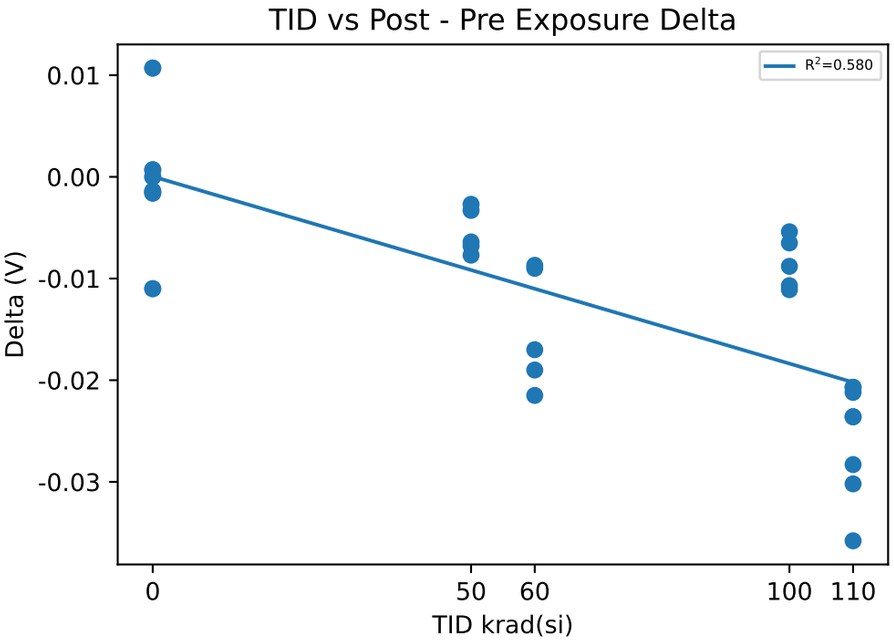
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	176.55	176.69	0.1412
2	0	CU2	182.58	182.66	0.0773
3	0	CU3	181.68	181.71	0.0266
11	50	Unbiased-50k	179.81	179.81	-0.0023
12	50	Unbiased-50k	175.73	175.56	-0.1665
13	50	Unbiased-50k	175.07	177.14	2.0701
14	50	Unbiased-50k	174.71	177.59	2.8769
16	50	Unbiased-50k	182.38	181.01	-1.3712
17	60	Biased-50k	179.43	173.63	-5.7974
18	60	Biased-50k	177.47	181.63	4.1563
19	60	Biased-50k	176.66	176.37	-0.2887
20	60	Biased-50k	183.42	179.61	-3.8103
21	60	Biased-50k	182.42	174.46	-7.9531
24	100	Unbiased-100k	171.46	175.26	3.7995
25	100	Unbiased-100k	180.4	178.35	-2.0537
26	100	Unbiased-100k	174.71	181.17	6.4574
27	100	Unbiased-100k	177.1	174.48	-2.6116
28	100	Unbiased-100k	183.78	183.41	-0.3707
29	110	Biased-100k	181.1	175.99	-5.1009
30	110	Biased-100k	182.53	179.96	-2.5696
31	110	Biased-100k	183.96	174.52	-9.4463
32	110	Biased-100k	180.67	173.9	-6.778
34	110	Biased-100k	178.08	179.78	1.7079

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	176.55	180.27	182.58	3.2531	176.69	180.35	182.66	3.2057	0.0266	0.0817	0.1412	0.057427
50	174.71	177.54	182.38	3.3919	175.56	178.22	181.01	2.1769	-1.3712	0.6814	2.8769	1.7427
60	176.66	179.88	183.42	2.973	173.63	177.14	181.63	3.4031	-7.9531	-2.7386	4.1563	4.7759
100	171.46	177.49	183.78	4.8024	174.48	178.53	183.41	3.8026	-2.6116	1.0442	6.4574	3.9325
110	178.08	181.27	183.96	2.2039	173.9	176.83	179.96	2.8792	-9.4463	-4.4374	1.7079	4.2503

Device Test: 42.3 UVLO_RISE_PVIN(THRESHOLD|RISE/PVIN3////90.9/634//0///@UVLO_RISE_PVIN)





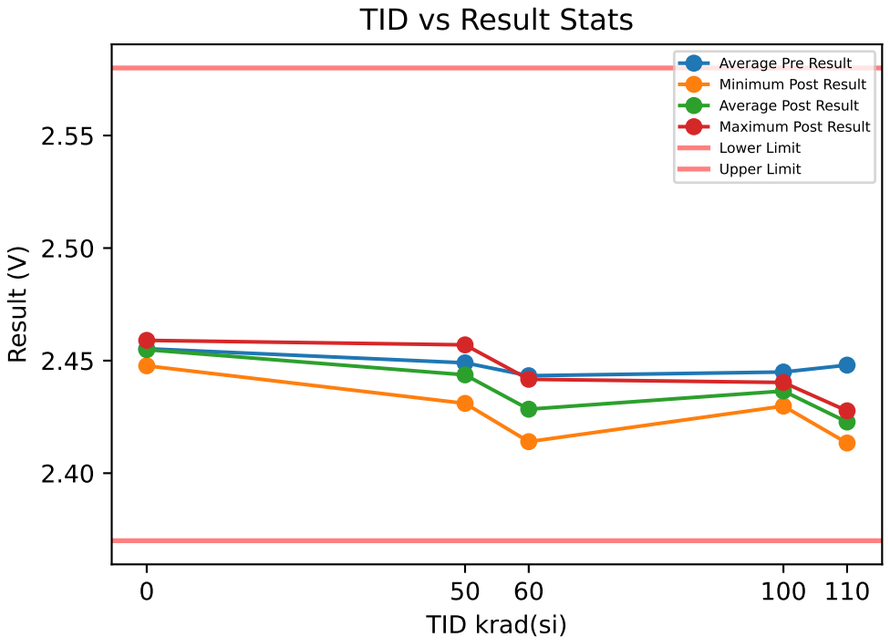
Test Results (Lower Limit = 2.37, Upper Limit = 2.58 (V))

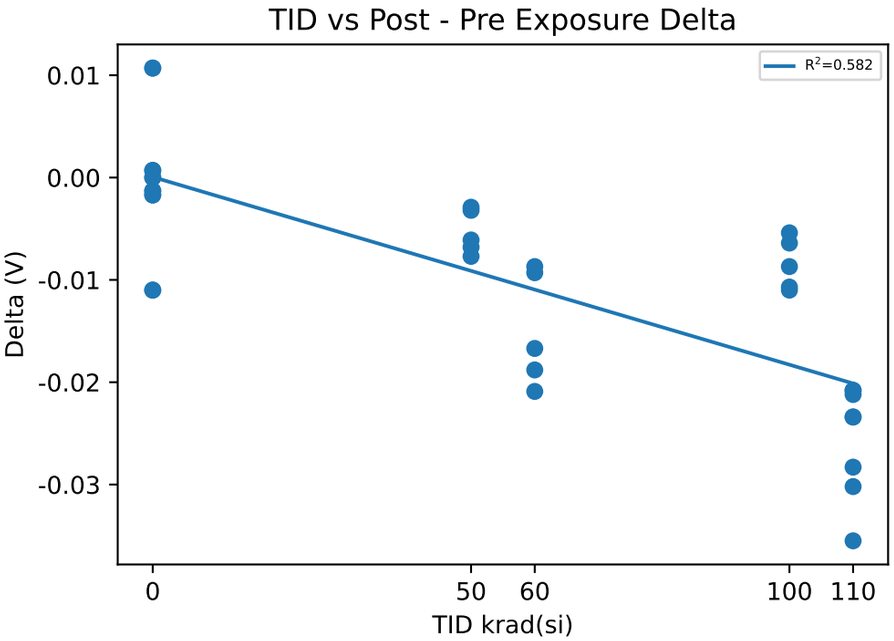
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4599	2.4583	-0.0016
2	0	CU2	2.447	2.4477	0.0007
3	0	CU3	2.459	2.459	0
11	50	Unbiased-50k	2.4602	2.4569	-0.0033
12	50	Unbiased-50k	2.4446	2.4419	-0.0027
13	50	Unbiased-50k	2.4476	2.4408	-0.0068
14	50	Unbiased-50k	2.4388	2.4311	-0.0077
16	50	Unbiased-50k	2.454	2.4476	-0.0064
17	60	Biased-50k	2.4399	2.4309	-0.009
18	60	Biased-50k	2.4484	2.4294	-0.019
19	60	Biased-50k	2.4348	2.4133	-0.0215
20	60	Biased-50k	2.4429	2.4259	-0.017
21	60	Biased-50k	2.4503	2.4416	-0.0087
24	100	Unbiased-100k	2.4489	2.4401	-0.0088
25	100	Unbiased-100k	2.4468	2.4403	-0.0065
26	100	Unbiased-100k	2.4352	2.4298	-0.0054
27	100	Unbiased-100k	2.4473	2.4366	-0.0107
28	100	Unbiased-100k	2.4466	2.4355	-0.0111
29	110	Biased-100k	2.4486	2.4203	-0.0283
30	110	Biased-100k	2.4455	2.4243	-0.0212
31	110	Biased-100k	2.449	2.4132	-0.0358
32	110	Biased-100k	2.4486	2.4184	-0.0302
34	110	Biased-100k	2.4484	2.4248	-0.0236

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.447	2.4553	2.4599	0.0072021	2.4477	2.455	2.459	0.0063317	-0.0016	-0.0003	0.0007	0.001179
50	2.4388	2.449	2.4602	0.0083035	2.4311	2.4437	2.4569	0.0094849	-0.0077	-0.00538	-0.0027	0.0022332
60	2.4348	2.4433	2.4503	0.0063042	2.4133	2.4282	2.4416	0.010193	-0.0215	-0.01504	-0.0087	0.0058722
100	2.4352	2.445	2.4489	0.0055302	2.4298	2.4365	2.4403	0.0042805	-0.0111	-0.0085	-0.0054	0.002515
110	2.4455	2.448	2.449	0.0014255	2.4132	2.4202	2.4248	0.0047492	-0.0358	-0.02782	-0.0212	0.0057273

Device Test: 42.4 UVLO_RISE_PVIN(THRESHOLD|RISE/PVIN4/////90.9/634//0///@UVLO_RISE_PVIN)





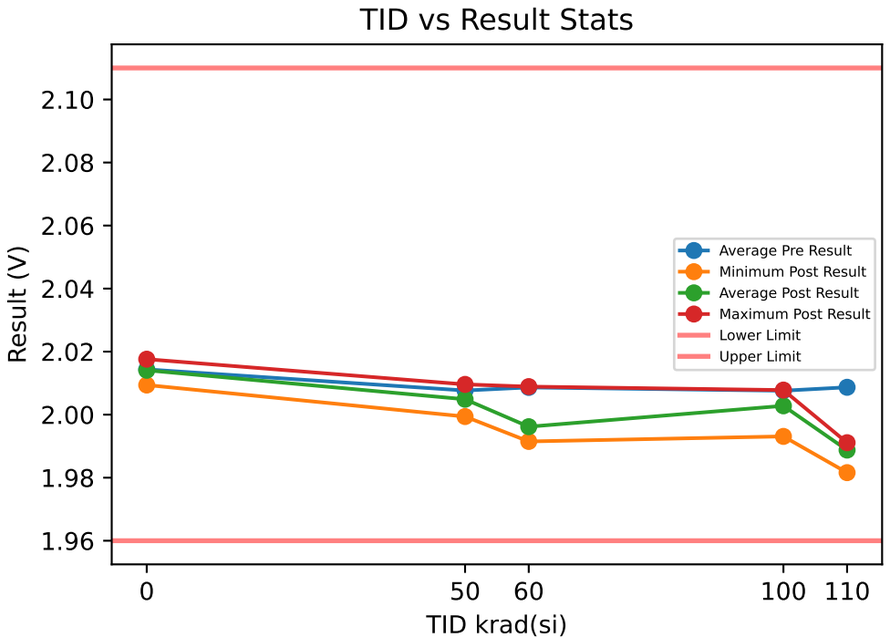
Test Results (Lower Limit = 2.37, Upper Limit = 2.58 (V))

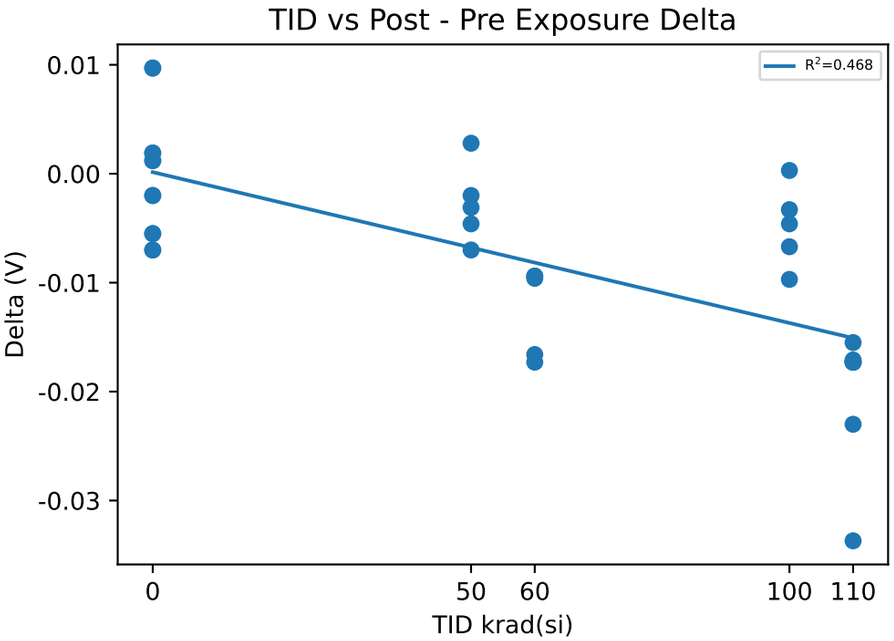
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.4599	2.4582	-0.0017
2	0	CU2	2.447	2.4477	0.0007
3	0	CU3	2.459	2.459	0
11	50	Unbiased-50k	2.4602	2.457	-0.0032
12	50	Unbiased-50k	2.4447	2.4418	-0.0029
13	50	Unbiased-50k	2.4476	2.4408	-0.0068
14	50	Unbiased-50k	2.4387	2.431	-0.0077
16	50	Unbiased-50k	2.4539	2.4478	-0.0061
17	60	Biased-50k	2.4399	2.4306	-0.0093
18	60	Biased-50k	2.4485	2.4297	-0.0188
19	60	Biased-50k	2.4349	2.414	-0.0209
20	60	Biased-50k	2.4428	2.4261	-0.0167
21	60	Biased-50k	2.4504	2.4417	-0.0087
24	100	Unbiased-100k	2.4489	2.4402	-0.0087
25	100	Unbiased-100k	2.4467	2.4403	-0.0064
26	100	Unbiased-100k	2.4352	2.4298	-0.0054
27	100	Unbiased-100k	2.4473	2.4366	-0.0107
28	100	Unbiased-100k	2.4466	2.4356	-0.011
29	110	Biased-100k	2.4486	2.4203	-0.0283
30	110	Biased-100k	2.4455	2.4243	-0.0212
31	110	Biased-100k	2.4489	2.4134	-0.0355
32	110	Biased-100k	2.4485	2.4183	-0.0302
34	110	Biased-100k	2.4485	2.4251	-0.0234

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.447	2.4553	2.4599	0.0072021	2.4477	2.455	2.459	0.0063058	-0.0017	-0.00033333	0.0007	0.0012342
50	2.4387	2.449	2.4602	0.0083064	2.431	2.4437	2.457	0.0095787	-0.0077	-0.00534	-0.0029	0.0021686
60	2.4349	2.4433	2.4504	0.006321	2.414	2.4284	2.4417	0.0099507	-0.0209	-0.01488	-0.0087	0.0055733
100	2.4352	2.4449	2.4489	0.005522	2.4298	2.4365	2.4403	0.0042965	-0.011	-0.00844	-0.0054	0.0025066
110	2.4455	2.448	2.4489	0.0014071	2.4134	2.4203	2.4251	0.0047605	-0.0355	-0.02772	-0.0212	0.005661

Device Test: 42.5 UVLO_FALL_PVIN(THRESHOLD|FALL/PVIN1////90.9/634//0///@UVLO_FALL_PVIN)





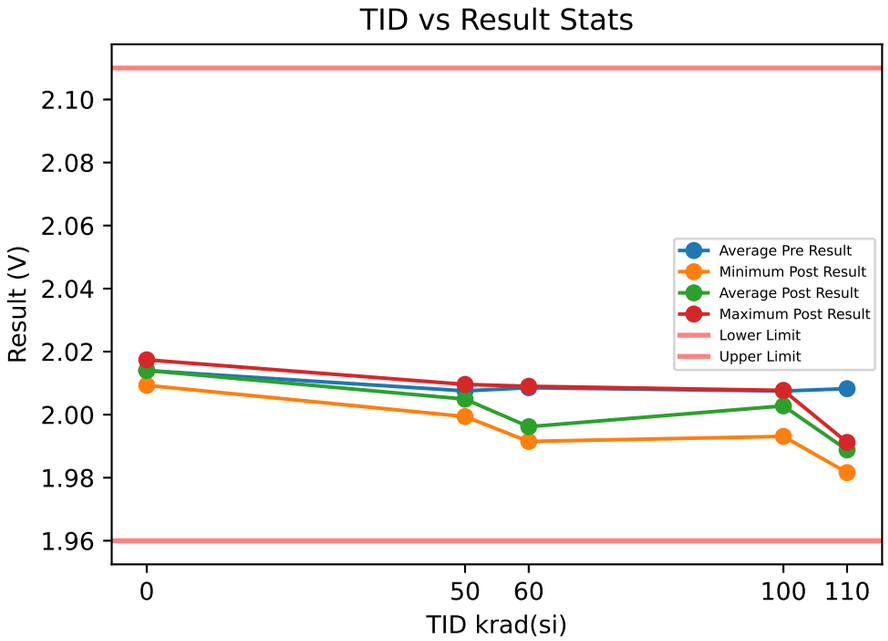
Test Results (Lower Limit = 1.96, Upper Limit = 2.11 (V))

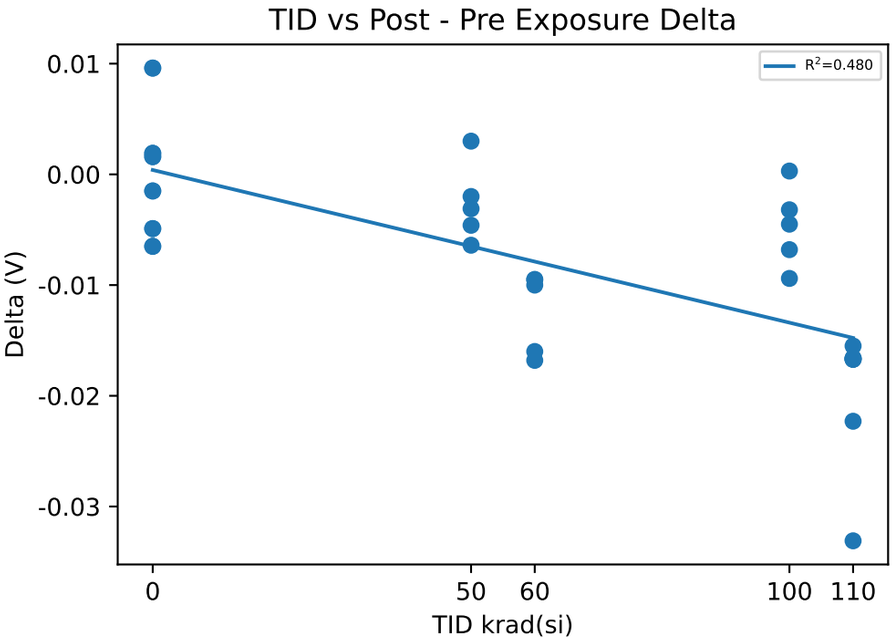
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.019	2.017	-0.002
2	0	CU2	2.0077	2.0096	0.0019
3	0	CU3	2.0164	2.0176	0.0012
11	50	Unbiased-50k	2.0142	2.0096	-0.0046
12	50	Unbiased-50k	2.0054	2.0034	-0.002
13	50	Unbiased-50k	2.0025	1.9994	-0.0031
14	50	Unbiased-50k	2.0046	2.0074	0.0028
16	50	Unbiased-50k	2.0116	2.0046	-0.007
17	60	Biased-50k	2.0081	1.9915	-0.0166
18	60	Biased-50k	2.006	1.9966	-0.0094
19	60	Biased-50k	2.0095	1.9922	-0.0173
20	60	Biased-50k	2.0013	1.9917	-0.0096
21	60	Biased-50k	2.0183	2.0089	-0.0094
24	100	Unbiased-100k	2.0107	2.001	-0.0097
25	100	Unbiased-100k	2.0056	2.0059	0.0003
26	100	Unbiased-100k	2.0108	2.0062	-0.0046
27	100	Unbiased-100k	1.9998	1.9931	-0.0067
28	100	Unbiased-100k	2.0111	2.0078	-0.0033
29	110	Biased-100k	2.0102	1.9872	-0.023
30	110	Biased-100k	2.0037	1.9882	-0.0155
31	110	Biased-100k	2.0058	1.9887	-0.0171
32	110	Biased-100k	2.0153	1.9816	-0.0337
34	110	Biased-100k	2.0084	1.9911	-0.0173

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0077	2.0144	2.019	0.0059181	2.0096	2.0147	2.0176	0.0044557	-0.002	0.00036667	0.0019	0.0020793
50	2.0025	2.0077	2.0142	0.0049848	1.9994	2.0049	2.0096	0.0039028	-0.007	-0.00278	0.0028	0.003639
60	2.0013	2.0086	2.0183	0.0062288	1.9915	1.9962	2.0089	0.0074126	-0.0173	-0.01246	-0.0094	0.0041071
100	1.9998	2.0076	2.0111	0.0049229	1.9931	2.0028	2.0078	0.0059896	-0.0097	-0.0048	0.0003	0.003739
110	2.0037	2.0087	2.0153	0.0044528	1.9816	1.9874	1.9911	0.0035246	-0.0337	-0.02132	-0.0155	0.0074821

Device Test: 42.6 UVLO_FALL_PVIN(THRESHOLD|FALL/PVIN2////90.9/634//0///@UVLO_FALL_PVIN)





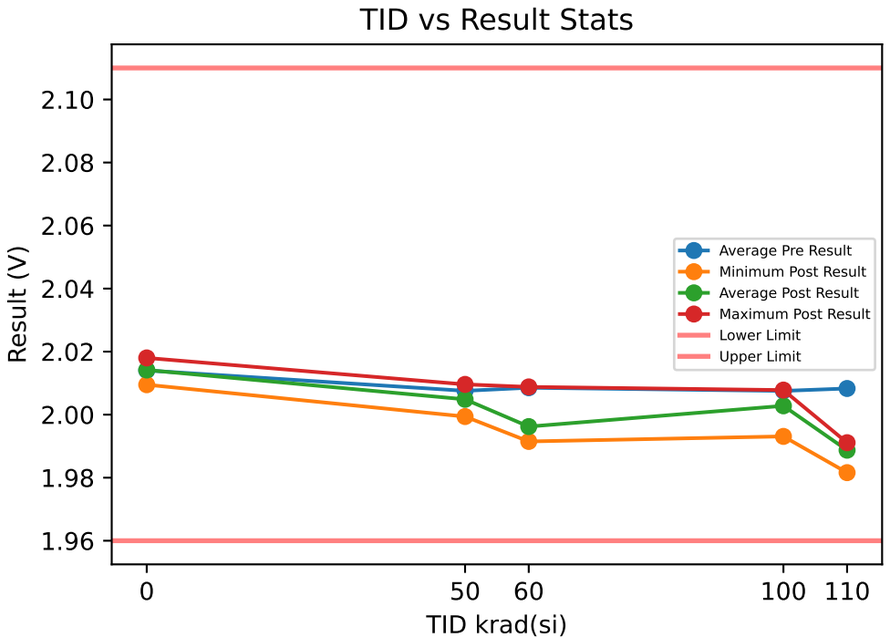
Test Results (Lower Limit = 1.96, Upper Limit = 2.11 (V))

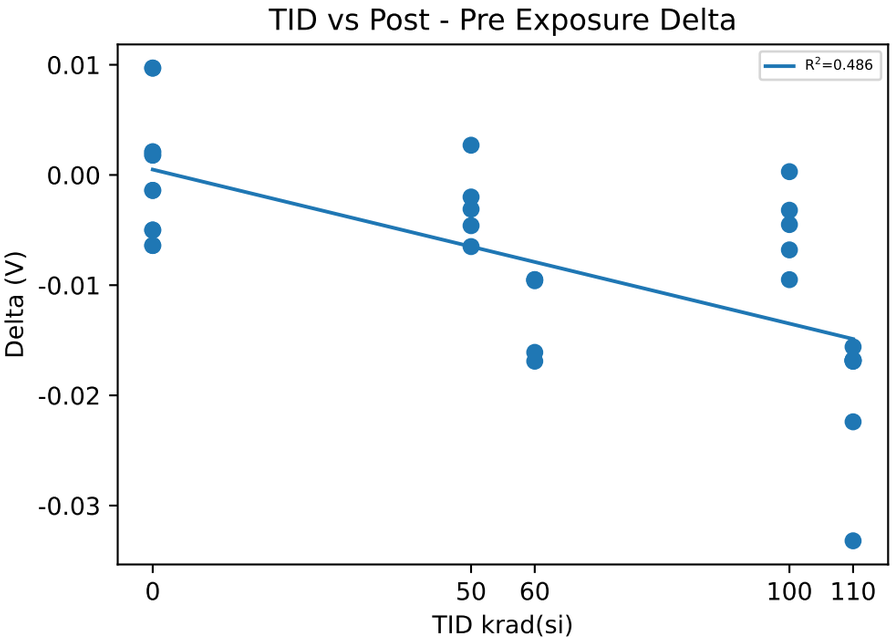
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0184	2.0169	-0.0015
2	0	CU2	2.0078	2.0097	0.0019
3	0	CU3	2.0158	2.0174	0.0016
11	50	Unbiased-50k	2.0142	2.0096	-0.0046
12	50	Unbiased-50k	2.0054	2.0034	-0.002
13	50	Unbiased-50k	2.0025	1.9994	-0.0031
14	50	Unbiased-50k	2.0046	2.0076	0.003
16	50	Unbiased-50k	2.011	2.0046	-0.0064
17	60	Biased-50k	2.0075	1.9915	-0.016
18	60	Biased-50k	2.0062	1.9967	-0.0095
19	60	Biased-50k	2.009	1.9922	-0.0168
20	60	Biased-50k	2.0015	1.9915	-0.01
21	60	Biased-50k	2.0185	2.009	-0.0095
24	100	Unbiased-100k	2.0104	2.001	-0.0094
25	100	Unbiased-100k	2.0056	2.0059	0.0003
26	100	Unbiased-100k	2.0107	2.0062	-0.0045
27	100	Unbiased-100k	1.9999	1.9931	-0.0068
28	100	Unbiased-100k	2.0109	2.0077	-0.0032
29	110	Biased-100k	2.0095	1.9872	-0.0223
30	110	Biased-100k	2.0037	1.9882	-0.0155
31	110	Biased-100k	2.0055	1.9888	-0.0167
32	110	Biased-100k	2.0147	1.9816	-0.0331
34	110	Biased-100k	2.0078	1.9912	-0.0166

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0078	2.014	2.0184	0.0055245	2.0097	2.0147	2.0174	0.0043085	-0.0015	0.00066667	0.0019	0.0018824
50	2.0025	2.0075	2.0142	0.0048722	1.9994	2.0049	2.0096	0.003936	-0.0064	-0.00262	0.003	0.0035499
60	2.0015	2.0085	2.0185	0.0062356	1.9915	1.9962	2.009	0.0074878	-0.0168	-0.01236	-0.0095	0.0037045
100	1.9999	2.0075	2.0109	0.0047849	1.9931	2.0028	2.0077	0.0059688	-0.0094	-0.00472	0.0003	0.003667
110	2.0037	2.0082	2.0147	0.0042318	1.9816	1.9874	1.9912	0.0035609	-0.0331	-0.02084	-0.0155	0.0073497

Device Test: 42.7 UVLO_FALL_PVIN(THRESHOLD|FALL/PVIN3////90.9/634//0///@UVLO_FALL_PVIN)





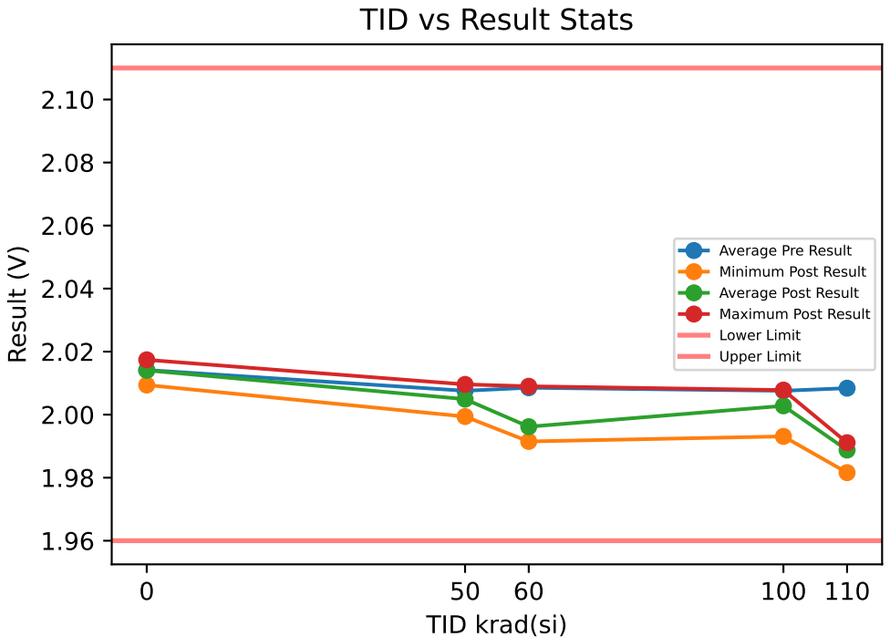
Test Results (Lower Limit = 1.96, Upper Limit = 2.11 (V))

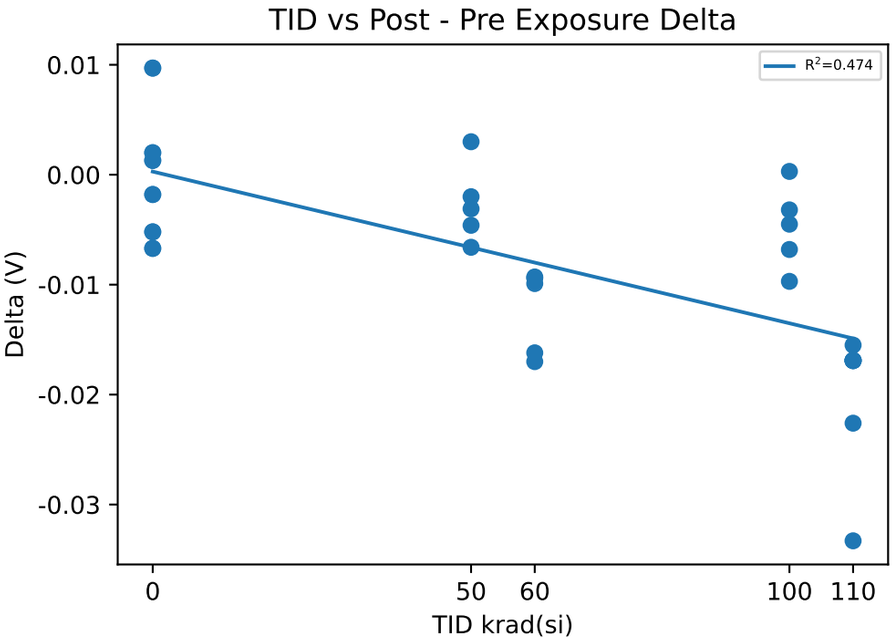
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0185	2.0171	-0.0014
2	0	CU2	2.0077	2.0095	0.0018
3	0	CU3	2.0159	2.018	0.0021
11	50	Unbiased-50k	2.0142	2.0096	-0.0046
12	50	Unbiased-50k	2.0054	2.0034	-0.002
13	50	Unbiased-50k	2.0025	1.9994	-0.0031
14	50	Unbiased-50k	2.0046	2.0073	0.0027
16	50	Unbiased-50k	2.0111	2.0046	-0.0065
17	60	Biased-50k	2.0076	1.9915	-0.0161
18	60	Biased-50k	2.0061	1.9966	-0.0095
19	60	Biased-50k	2.0091	1.9922	-0.0169
20	60	Biased-50k	2.0015	1.992	-0.0095
21	60	Biased-50k	2.0184	2.0088	-0.0096
24	100	Unbiased-100k	2.0105	2.001	-0.0095
25	100	Unbiased-100k	2.0056	2.0059	0.0003
26	100	Unbiased-100k	2.0107	2.0062	-0.0045
27	100	Unbiased-100k	1.9999	1.9931	-0.0068
28	100	Unbiased-100k	2.011	2.0078	-0.0032
29	110	Biased-100k	2.0096	1.9872	-0.0224
30	110	Biased-100k	2.0037	1.9881	-0.0156
31	110	Biased-100k	2.0055	1.9887	-0.0168
32	110	Biased-100k	2.0148	1.9816	-0.0332
34	110	Biased-100k	2.0079	1.9911	-0.0168

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0077	2.014	2.0185	0.0056368	2.0095	2.0149	2.018	0.0046694	-0.0014	0.00083333	0.0021	0.0019399
50	2.0025	2.0076	2.0142	0.0048901	1.9994	2.0049	2.0096	0.0038869	-0.0065	-0.0027	0.0027	0.003459
60	2.0015	2.0085	2.0184	0.0062035	1.9915	1.9962	2.0088	0.0073254	-0.0169	-0.01232	-0.0095	0.0038265
100	1.9999	2.0075	2.011	0.004818	1.9931	2.0028	2.0078	0.0059896	-0.0095	-0.00474	0.0003	0.0036991
110	2.0037	2.0083	2.0148	0.0042749	1.9816	1.9873	1.9911	0.0035189	-0.0332	-0.02096	-0.0156	0.0073354

Device Test: 42.8 UVLO_FALL_PVIN(THRESHOLD|FALL/PVIN4/////90.9/634//0///@UVLO_FALL_PVIN)





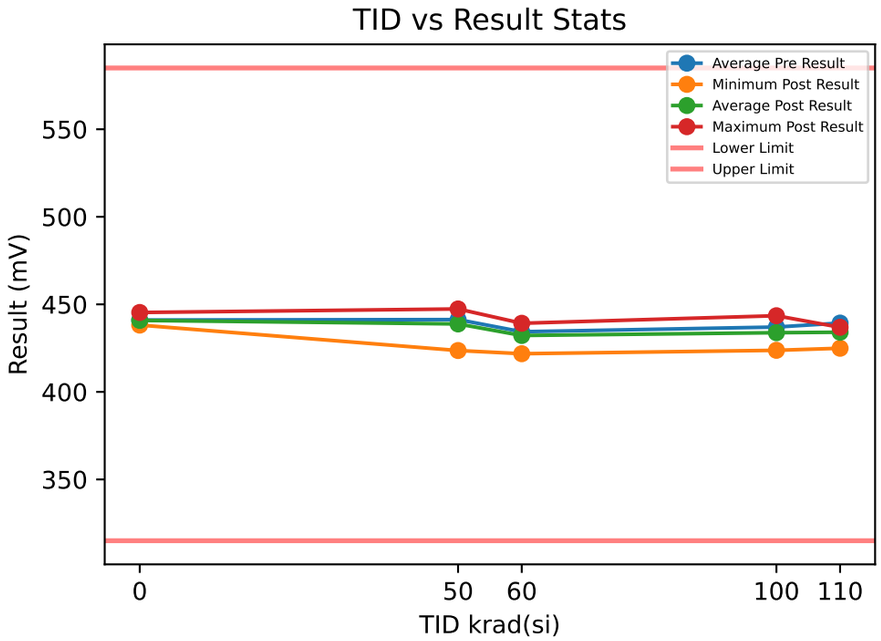
Test Results (Lower Limit = 1.96, Upper Limit = 2.11 (V))

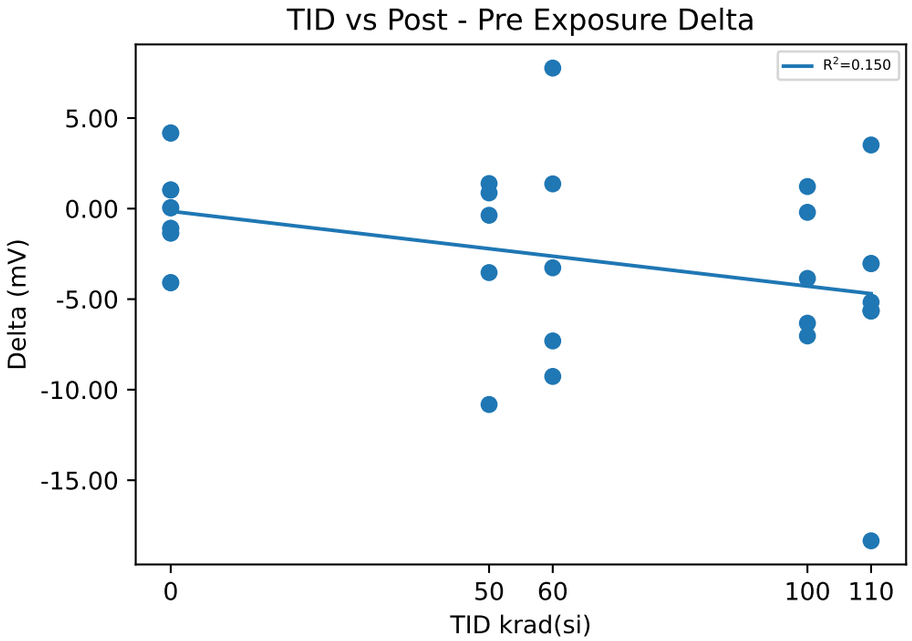
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.0187	2.0169	-0.0018
2	0	CU2	2.0077	2.0097	0.002
3	0	CU3	2.0161	2.0174	0.0013
11	50	Unbiased-50k	2.0142	2.0096	-0.0046
12	50	Unbiased-50k	2.0054	2.0034	-0.002
13	50	Unbiased-50k	2.0025	1.9994	-0.0031
14	50	Unbiased-50k	2.0046	2.0076	0.003
16	50	Unbiased-50k	2.0112	2.0046	-0.0066
17	60	Biased-50k	2.0077	1.9915	-0.0162
18	60	Biased-50k	2.0061	1.9967	-0.0094
19	60	Biased-50k	2.0092	1.9922	-0.017
20	60	Biased-50k	2.0014	1.9915	-0.0099
21	60	Biased-50k	2.0183	2.009	-0.0093
24	100	Unbiased-100k	2.0107	2.001	-0.0097
25	100	Unbiased-100k	2.0056	2.0059	0.0003
26	100	Unbiased-100k	2.0107	2.0062	-0.0045
27	100	Unbiased-100k	1.9999	1.9931	-0.0068
28	100	Unbiased-100k	2.011	2.0078	-0.0032
29	110	Biased-100k	2.0098	1.9872	-0.0226
30	110	Biased-100k	2.0037	1.9882	-0.0155
31	110	Biased-100k	2.0056	1.9887	-0.0169
32	110	Biased-100k	2.0149	1.9816	-0.0333
34	110	Biased-100k	2.008	1.9911	-0.0169

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.0077	2.0142	2.0187	0.0057492	2.0097	2.0147	2.0174	0.0043085	-0.0018	0.0005	0.002	0.0020224
50	2.0025	2.0076	2.0142	0.0049084	1.9994	2.0049	2.0096	0.003936	-0.0066	-0.00266	0.003	0.0036039
60	2.0014	2.0085	2.0183	0.0061914	1.9915	1.9962	2.009	0.0074878	-0.017	-0.01236	-0.0093	0.0038875
100	1.9999	2.0076	2.011	0.0048494	1.9931	2.0028	2.0078	0.0059896	-0.0097	-0.00478	0.0003	0.0037639
110	2.0037	2.0084	2.0149	0.0043099	1.9816	1.9874	1.9911	0.0035246	-0.0333	-0.02104	-0.0155	0.0073775

Device Test: 42.9 UVLO_HYST_PVIN(THRESHOLD|HYST/PVIN1/////90.9/634//0///@UVLO_HYST_PVIN)





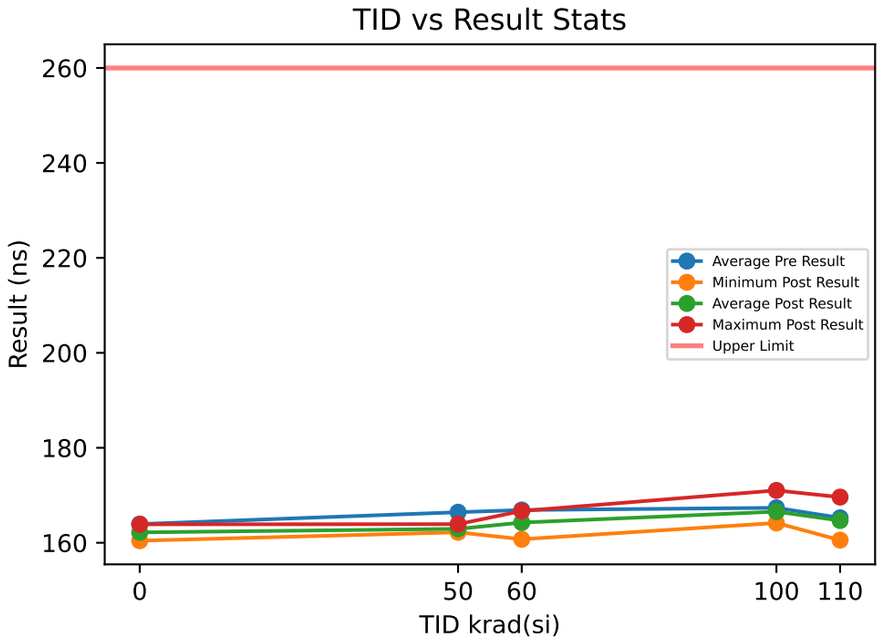
Test Results (Lower Limit = 315.0, Upper Limit = 585.0 (mV))

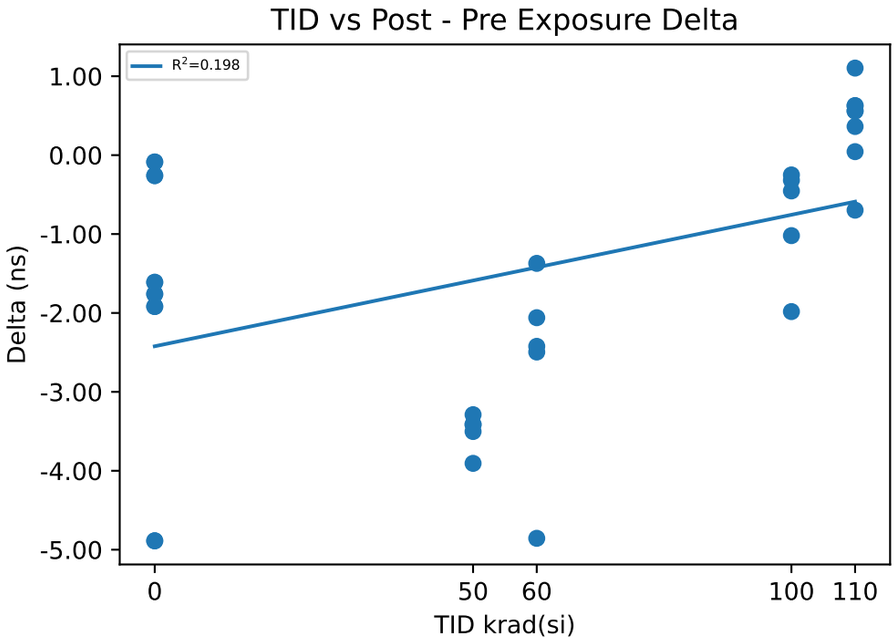
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	441.19	441.23	0.0472
2	0	CU2	439.24	438.15	-1.0916
3	0	CU3	442.7	441.35	-1.3498
11	50	Unbiased-50k	445.98	447.37	1.3848
12	50	Unbiased-50k	438.83	438.46	-0.3686
13	50	Unbiased-50k	444.97	441.43	-3.533
14	50	Unbiased-50k	434.44	423.62	-10.817
16	50	Unbiased-50k	442.29	443.15	0.8664
17	60	Biased-50k	431.43	439.19	7.7604
18	60	Biased-50k	442.24	432.97	-9.2678
19	60	Biased-50k	425.07	421.81	-3.2693
20	60	Biased-50k	441.71	434.41	-7.3074
21	60	Biased-50k	431.36	432.72	1.3645
24	100	Unbiased-100k	438.06	439.28	1.2193
25	100	Unbiased-100k	440.83	434.5	-6.3279
26	100	Unbiased-100k	423.95	423.74	-0.2049
27	100	Unbiased-100k	447.35	443.5	-3.8555
28	100	Unbiased-100k	435.01	427.98	-7.032
29	110	Biased-100k	438.34	433.17	-5.1682
30	110	Biased-100k	441.84	436.22	-5.6171
31	110	Biased-100k	443.27	424.92	-18.346
32	110	Biased-100k	433.38	436.89	3.5126
34	110	Biased-100k	439.7	434.05	-5.654

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	439.24	441.04	442.7	1.7363	438.15	440.24	441.35	1.8169	-1.3498	-0.79807	0.0472	0.74332
50	434.44	441.3	445.98	4.7313	423.62	438.81	447.37	9.08	-10.817	-2.4935	1.3848	5.03
60	425.07	434.36	442.24	7.4151	421.81	432.22	439.19	6.377	-9.2678	-2.1439	7.7604	6.8754
100	423.95	437.04	447.35	8.6209	423.74	433.8	443.5	8.0569	-7.032	-3.2402	1.2193	3.6534
110	433.38	439.3	443.27	3.8189	424.92	433.05	436.89	4.792	-18.346	-6.2545	3.5126	7.8029

Device Test: 45.1 MIN_ON_TIME_VIN_3V(OnDeadTime|ON_TIME/SW1/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V)





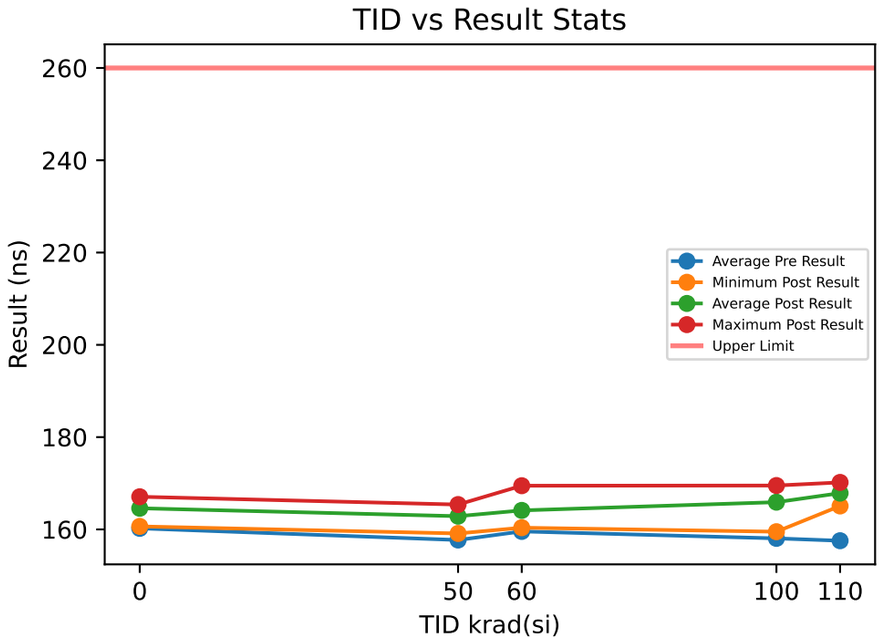
Test Results (Upper Limit = 260.0 (ns))

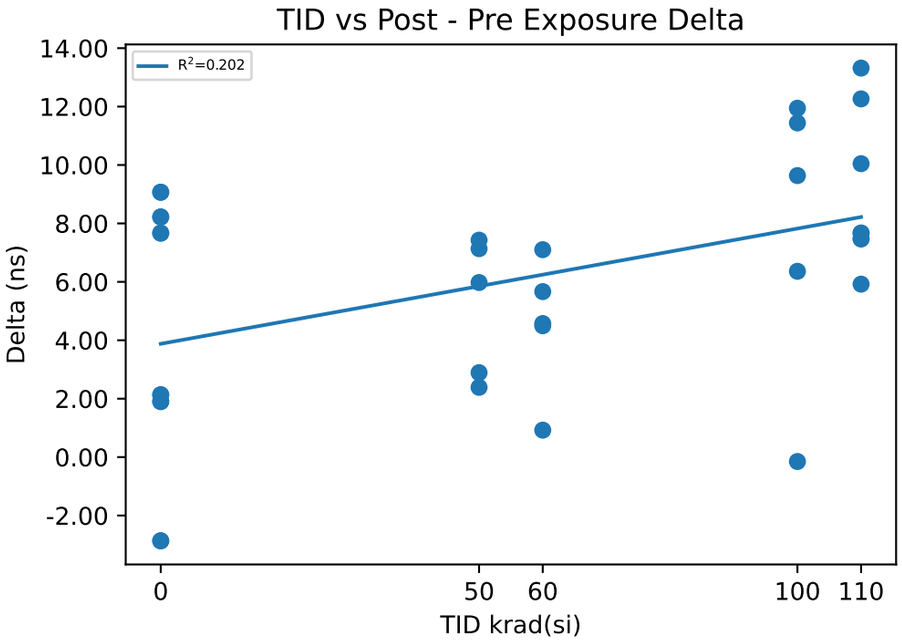
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	162.19	160.43	-1.7602
2	0	CU2	165.8	163.88	-1.9181
3	0	CU3	163.81	162.2	-1.6115
11	50	Unbiased-50k	166.47	163.05	-3.4116
12	50	Unbiased-50k	166.12	162.62	-3.5024
13	50	Unbiased-50k	167.82	163.92	-3.906
14	50	Unbiased-50k	165.62	162.21	-3.4156
16	50	Unbiased-50k	166.13	162.84	-3.2891
17	60	Biased-50k	167.63	165.13	-2.4951
18	60	Biased-50k	168.68	163.82	-4.8558
19	60	Biased-50k	166.94	164.88	-2.0601
20	60	Biased-50k	169.11	166.69	-2.4232
21	60	Biased-50k	162.11	160.74	-1.3717
24	100	Unbiased-100k	165.88	165.42	-0.4537
25	100	Unbiased-100k	171.34	171.02	-0.3184
26	100	Unbiased-100k	166.69	166.44	-0.2509
27	100	Unbiased-100k	167.68	165.7	-1.9827
28	100	Unbiased-100k	165.19	164.17	-1.0201
29	110	Biased-100k	167.05	167.1	0.0441
30	110	Biased-100k	159.45	160.56	1.1032
31	110	Biased-100k	170.31	169.61	-0.6975
32	110	Biased-100k	166.77	167.13	0.3629
34	110	Biased-100k	162.66	163.22	0.56

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	162.19	163.93	165.8	1.8092	160.43	162.17	163.88	1.7273	-1.9181	-1.7633	-1.6115	0.15332
50	165.62	166.43	167.82	0.83471	162.21	162.93	163.92	0.63685	-3.906	-3.5049	-3.2891	0.23672
60	162.11	166.89	169.11	2.808	160.74	164.25	166.69	2.2157	-4.8558	-2.6412	-1.3717	1.3155
100	165.19	167.36	171.34	2.4147	164.17	166.55	171.02	2.6313	-1.9827	-0.80516	-0.2509	0.72465
110	159.45	165.25	170.31	4.2275	160.56	165.52	169.61	3.5977	-0.6975	0.27454	1.1032	0.66595

Device Test: 45.2 MIN_ON_TIME_VIN_3V(OnDeadTime|ON_TIME/SW2/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V)





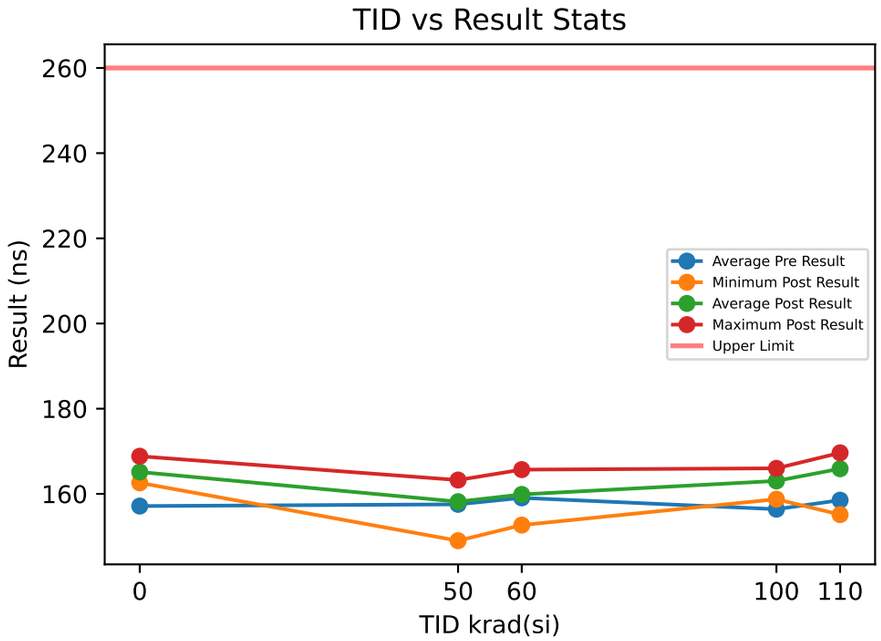
Test Results (Upper Limit = 260.0 (ns))

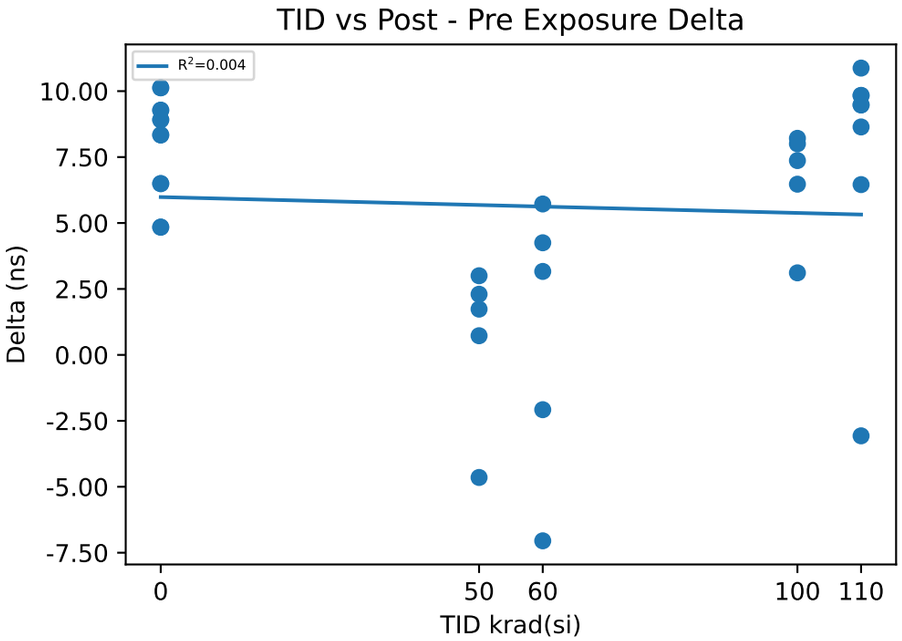
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	163.92	161.06	-2.8659
2	0	CU2	158.75	166.42	7.6684
3	0	CU3	158.01	166.23	8.2207
11	50	Unbiased-50k	156.73	159.12	2.3886
12	50	Unbiased-50k	154.17	161.6	7.4275
13	50	Unbiased-50k	158.25	165.39	7.1355
14	50	Unbiased-50k	157.83	163.81	5.9768
16	50	Unbiased-50k	161.52	164.41	2.8908
17	60	Biased-50k	154.47	161.57	7.101
18	60	Biased-50k	163.8	169.47	5.6654
19	60	Biased-50k	155.8	160.37	4.5722
20	60	Biased-50k	162.43	166.93	4.4967
21	60	Biased-50k	161.32	162.25	0.923
24	100	Unbiased-100k	157.9	169.34	11.44
25	100	Unbiased-100k	158.76	165.12	6.3612
26	100	Unbiased-100k	157.56	169.51	11.944
27	100	Unbiased-100k	156.41	166.05	9.6376
28	100	Unbiased-100k	159.65	159.5	-0.1508
29	110	Biased-100k	155.03	165.08	10.045
30	110	Biased-100k	159.89	165.81	5.9206
31	110	Biased-100k	156.87	170.19	13.318
32	110	Biased-100k	154.86	167.12	12.263
34	110	Biased-100k	161.1	168.57	7.4714

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	158.01	160.23	163.92	3.2215	161.06	164.57	166.42	3.0428	-2.8659	4.3411	8.2207	6.2475
50	154.17	157.7	161.52	2.6605	159.12	162.87	165.39	2.5127	2.3886	5.1638	7.4275	2.3739
60	154.47	159.57	163.8	4.1678	160.37	164.12	169.47	3.8924	0.923	4.5517	7.101	2.2864
100	156.41	158.06	159.65	1.228	159.5	165.9	169.51	4.0737	-0.1508	7.8463	11.944	4.9767
110	154.86	157.55	161.1	2.8313	165.08	167.35	170.19	2.0679	5.9206	9.8038	13.318	3.1216

Device Test: 45.3 MIN_ON_TIME_VIN_3V(OnDeadTime|ON_TIME/SW3/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V)





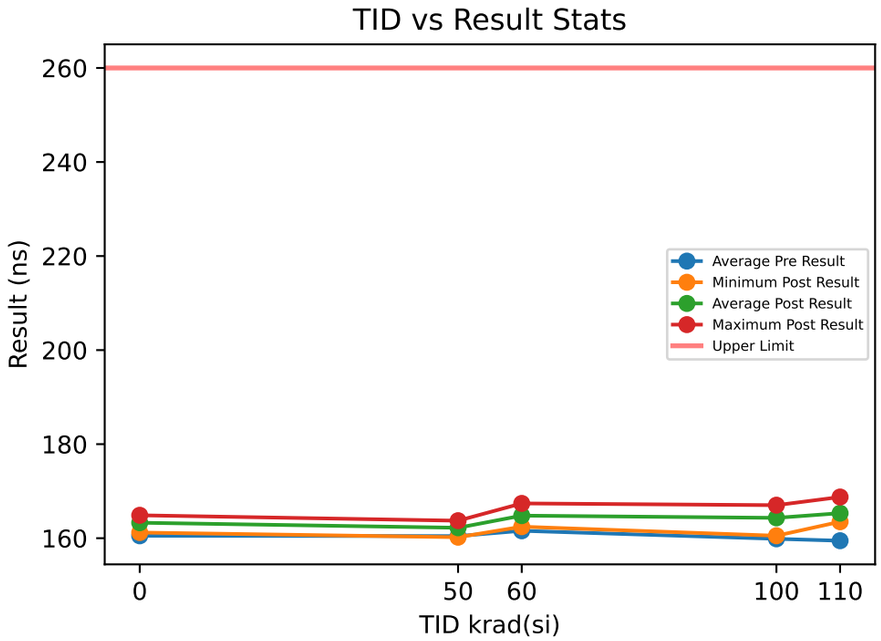
Test Results (Upper Limit = 260.0 (ns))

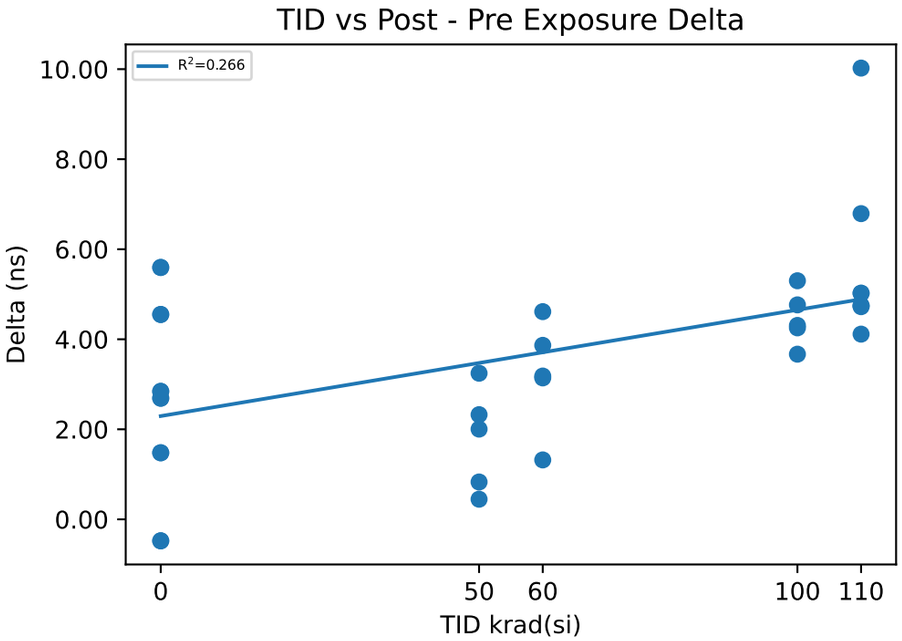
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	159.92	164.76	4.8431
2	0	CU2	156.1	162.59	6.4935
3	0	CU3	155.4	165.52	10.127
11	50	Unbiased-50k	153.64	149	-4.6473
12	50	Unbiased-50k	159.53	160.26	0.7261
13	50	Unbiased-50k	156.32	159.32	3.0006
14	50	Unbiased-50k	156.7	159	2.3001
16	50	Unbiased-50k	161.51	163.25	1.7353
17	60	Biased-50k	154.74	152.67	-2.0777
18	60	Biased-50k	158.55	162.8	4.2509
19	60	Biased-50k	160.32	153.27	-7.0492
20	60	Biased-50k	162.53	165.69	3.1645
21	60	Biased-50k	159.17	164.89	5.7219
24	100	Unbiased-100k	157.16	165.37	8.2108
25	100	Unbiased-100k	155.64	158.75	3.1105
26	100	Unbiased-100k	157.99	165.99	8.0026
27	100	Unbiased-100k	157.05	163.52	6.4721
28	100	Unbiased-100k	154.17	161.53	7.3673
29	110	Biased-100k	158.2	155.13	-3.0687
30	110	Biased-100k	159.32	165.77	6.4561
31	110	Biased-100k	158.76	169.63	10.874
32	110	Biased-100k	158.59	167.23	8.642
34	110	Biased-100k	157.7	167.53	9.8367

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	155.4	157.14	159.92	2.4334	162.59	164.29	165.52	1.5217	4.8431	7.1546	10.127	2.7034
50	153.64	157.54	161.51	3.0454	149	158.16	163.25	5.3912	-4.6473	0.62296	3.0006	3.0614
60	154.74	159.06	162.53	2.8503	152.67	159.86	165.69	6.3858	-7.0492	0.80208	5.7219	5.2824
100	154.17	156.4	157.99	1.5088	158.75	163.03	165.99	2.9627	3.1105	6.6327	8.2108	2.082
110	157.7	158.51	159.32	0.60766	155.13	165.06	169.63	5.7197	-3.0687	6.5481	10.874	5.6215

Device Test: 45.4 MIN_ON_TIME_VIN_3V(OnDeadTime|ON_TIME/SW4/3/3///90.9/634//0///@MIN_ON_TIME_VIN_3V)





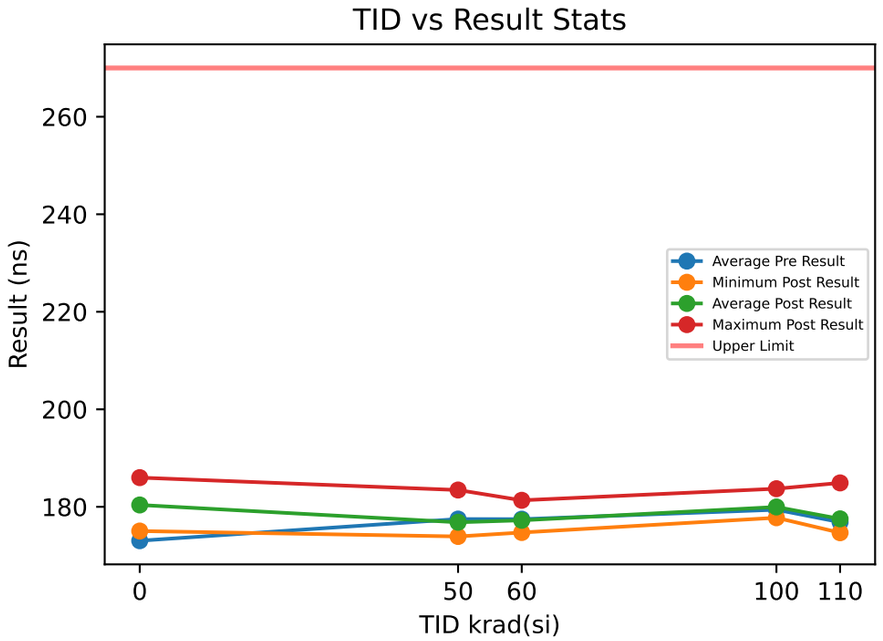
Test Results (Upper Limit = 260.0 (ns))

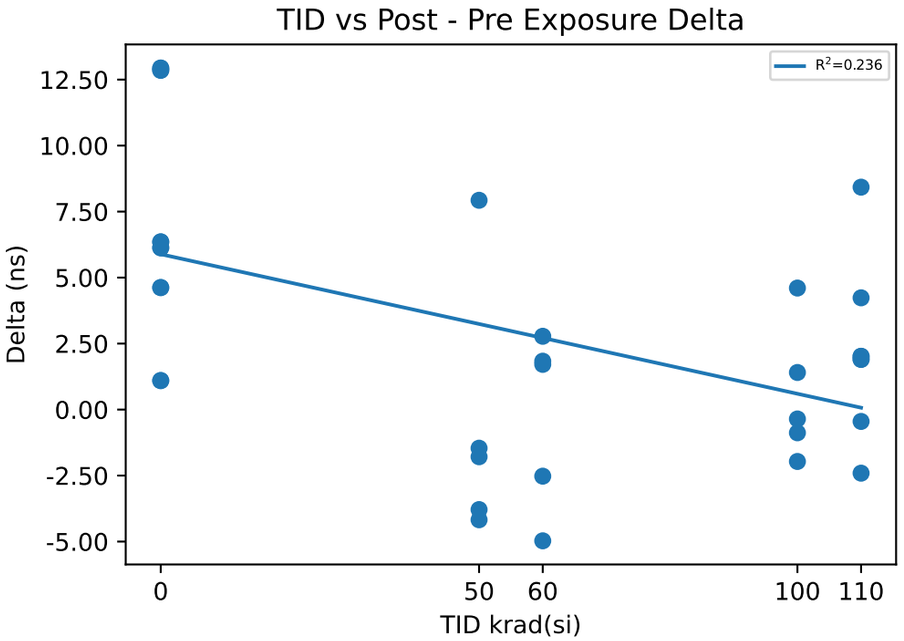
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	162.7	162.22	-0.4774
2	0	CU2	160.32	164.87	4.5507
3	0	CU3	158.51	161.2	2.691
11	50	Unbiased-50k	161.32	163.33	2.0044
12	50	Unbiased-50k	159.07	161.39	2.325
13	50	Unbiased-50k	159.2	162.44	3.2452
14	50	Unbiased-50k	162.89	163.72	0.8294
16	50	Unbiased-50k	159.76	160.21	0.4468
17	60	Biased-50k	160.63	163.78	3.1417
18	60	Biased-50k	161.37	164.55	3.1826
19	60	Biased-50k	161.96	165.82	3.8649
20	60	Biased-50k	162.78	167.39	4.6136
21	60	Biased-50k	161.13	162.45	1.3197
24	100	Unbiased-100k	161.51	165.82	4.3071
25	100	Unbiased-100k	159.09	164.39	5.2995
26	100	Unbiased-100k	162.26	167.02	4.7638
27	100	Unbiased-100k	160.2	163.87	3.6685
28	100	Unbiased-100k	156.27	160.52	4.2533
29	110	Biased-100k	158.88	165.67	6.7905
30	110	Biased-100k	159.38	163.5	4.1138
31	110	Biased-100k	160.31	165.03	4.7237
32	110	Biased-100k	158.73	168.76	10.024
34	110	Biased-100k	160.01	165.03	5.0229

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	158.51	160.51	162.7	2.1011	161.2	162.76	164.87	1.8942	-0.4774	2.2548	4.5507	2.5423
50	159.07	160.45	162.89	1.6341	160.21	162.22	163.72	1.4371	0.4468	1.7702	3.2452	1.1374
60	160.63	161.57	162.78	0.82571	162.45	164.8	167.39	1.8991	1.3197	3.2245	4.6136	1.2224
100	156.27	159.87	162.26	2.3487	160.52	164.32	167.02	2.4582	3.6685	4.4584	5.2995	0.61025
110	158.73	159.46	160.31	0.69026	163.5	165.6	168.76	1.9381	4.1138	6.135	10.024	2.391

Device Test: 46.1 MIN_ON_TIME_VIN_5V(OnDeadTime|ON_TIME/SW1/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V)





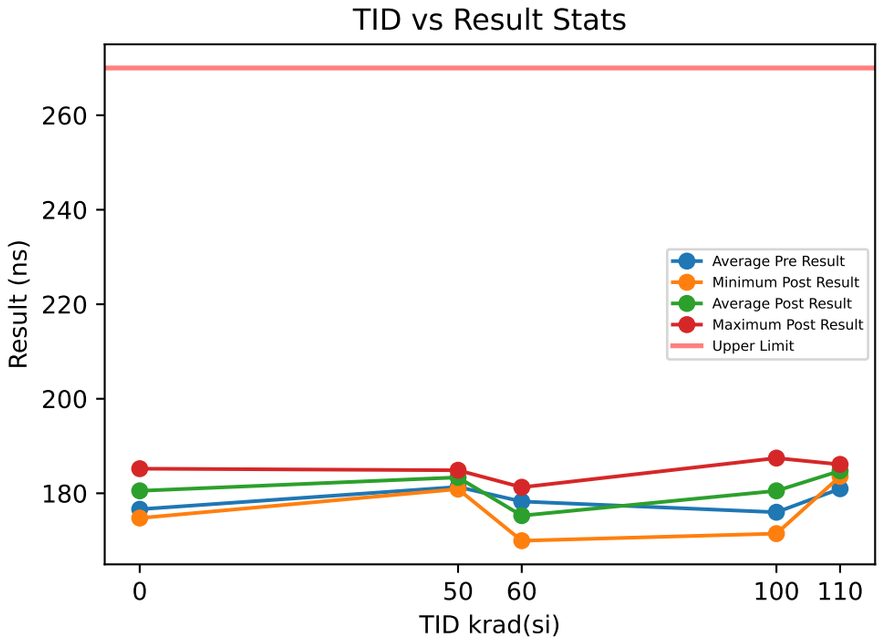
Test Results (Upper Limit = 270.0 (ns))

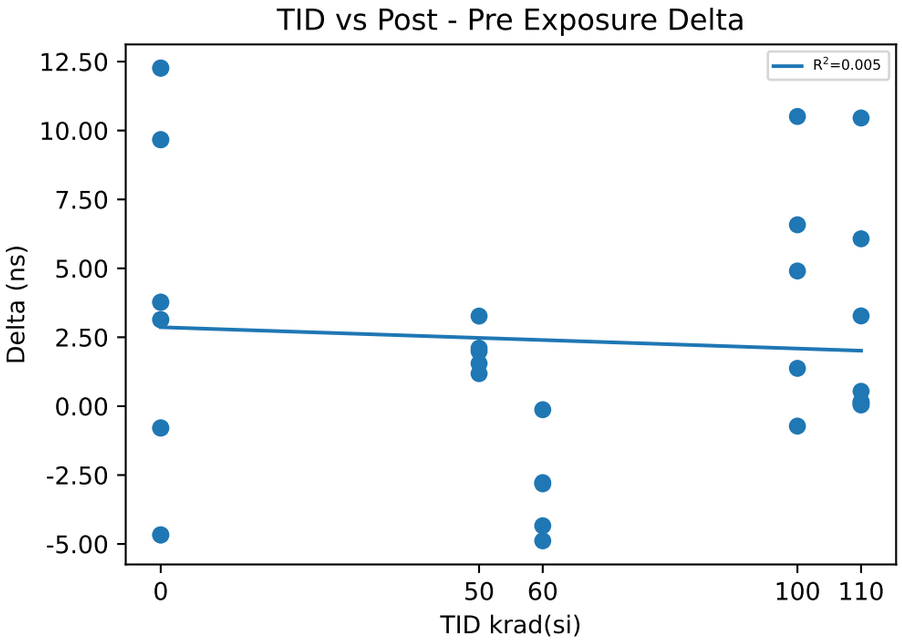
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	173.05	185.99	12.937
2	0	CU2	173.94	175.03	1.0984
3	0	CU3	172.16	176.78	4.6218
11	50	Unbiased-50k	179.2	175.03	-4.1743
12	50	Unbiased-50k	177.71	173.92	-3.7883
13	50	Unbiased-50k	178.68	176.9	-1.7867
14	50	Unbiased-50k	176.33	174.87	-1.4626
16	50	Unbiased-50k	175.52	183.45	7.9285
17	60	Biased-50k	178.87	176.35	-2.5226
18	60	Biased-50k	177.1	178.93	1.8333
19	60	Biased-50k	179.79	174.82	-4.9716
20	60	Biased-50k	178.56	181.34	2.7769
21	60	Biased-50k	173.02	174.73	1.7128
24	100	Unbiased-100k	176.36	177.76	1.4049
25	100	Unbiased-100k	184.07	183.71	-0.3558
26	100	Unbiased-100k	179.63	178.75	-0.8792
27	100	Unbiased-100k	180.62	178.65	-1.966
28	100	Unbiased-100k	176.35	180.96	4.6037
29	110	Biased-100k	181.5	179.09	-2.4087
30	110	Biased-100k	170.01	178.44	8.4256
31	110	Biased-100k	180.67	184.91	4.2338
32	110	Biased-100k	179.32	178.87	-0.449
34	110	Biased-100k	172.79	174.81	2.018

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	172.16	173.05	173.94	0.88821	175.03	179.27	185.99	5.8862	1.0984	6.219	12.937	6.0787
50	175.52	177.49	179.2	1.5515	173.92	176.83	183.45	3.8518	-4.1743	-0.65668	7.9285	4.945
60	173.02	177.47	179.79	2.668	174.73	177.23	181.34	2.8554	-4.9716	-0.23424	2.7769	3.3471
100	176.35	179.41	184.07	3.2362	177.76	179.97	183.71	2.4024	-1.966	0.56152	4.6037	2.5669
110	170.01	176.86	181.5	5.1372	174.81	179.22	184.91	3.6251	-2.4087	2.3639	8.4256	4.2146

Device Test: 46.2 MIN_ON_TIME_VIN_5V(OnDeadTime|ON_TIME/SW2/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V)





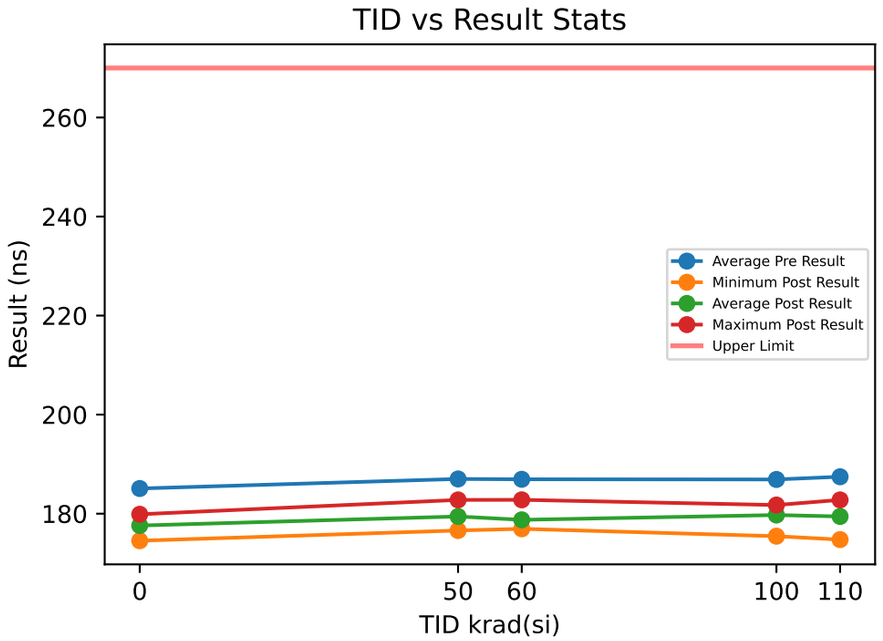
Test Results (Upper Limit = 270.0 (ns))

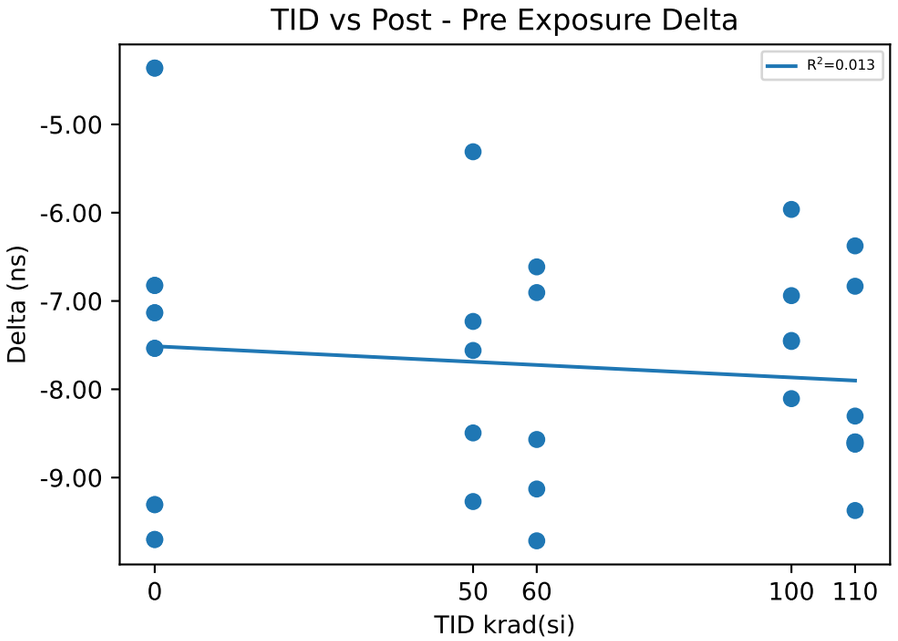
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	172.94	182.6	9.6658
2	0	CU2	175.55	174.76	-0.7914
3	0	CU3	181.38	185.15	3.7708
11	50	Unbiased-50k	178.89	180.88	1.9884
12	50	Unbiased-50k	180.42	182.52	2.1041
13	50	Unbiased-50k	183.69	184.87	1.1804
14	50	Unbiased-50k	180.73	184	3.2682
16	50	Unbiased-50k	182.98	184.53	1.5494
17	60	Biased-50k	181.21	176.33	-4.8856
18	60	Biased-50k	181.4	181.27	-0.1287
19	60	Biased-50k	179.06	174.72	-4.3386
20	60	Biased-50k	176.86	174.09	-2.7743
21	60	Biased-50k	172.78	169.96	-2.818
24	100	Unbiased-100k	176	180.9	4.9045
25	100	Unbiased-100k	178.14	184.72	6.5794
26	100	Unbiased-100k	176.68	178.05	1.3715
27	100	Unbiased-100k	176.94	187.45	10.51
28	100	Unbiased-100k	172.19	171.46	-0.7233
29	110	Biased-100k	175.66	186.11	10.455
30	110	Biased-100k	183.04	183.58	0.539
31	110	Biased-100k	181.92	185.2	3.274
32	110	Biased-100k	180.03	186.1	6.0718
34	110	Biased-100k	184.14	184.3	0.1554

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	172.94	176.62	181.38	4.324	174.76	180.84	185.15	5.4181	-0.7914	4.2151	9.6658	5.2427
50	178.89	181.34	183.69	1.9649	180.88	183.36	184.87	1.6523	1.1804	2.0181	3.2682	0.78937
60	172.78	178.26	181.4	3.5782	169.96	175.27	181.27	4.094	-4.8856	-2.989	-0.1287	1.849
100	172.19	175.99	178.14	2.2622	171.46	180.52	187.45	6.203	-0.7233	4.5284	10.51	4.4066
110	175.66	180.96	184.14	3.3306	183.58	185.06	186.11	1.1154	0.1554	4.099	10.455	4.2776

Device Test: 46.3 MIN_ON_TIME_VIN_5V(OnDeadTime|ON_TIME/SW3/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V)





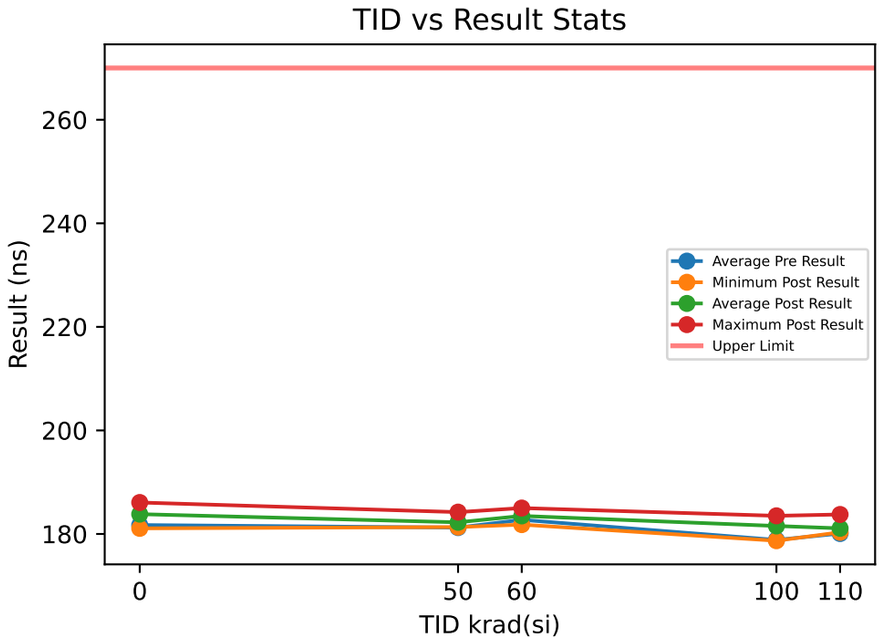
Test Results (Upper Limit = 270.0 (ns))

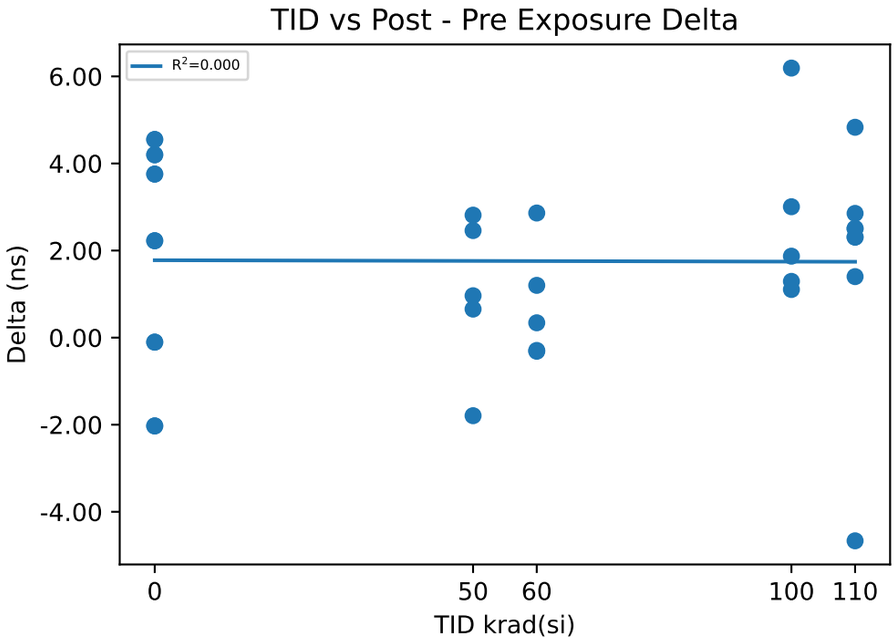
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	184.24	174.54	-9.7011
2	0	CU2	185.82	178.69	-7.1333
3	0	CU3	185.18	177.65	-7.5361
11	50	Unbiased-50k	185.19	179.88	-5.3098
12	50	Unbiased-50k	190.01	182.78	-7.2315
13	50	Unbiased-50k	187.82	180.26	-7.5604
14	50	Unbiased-50k	186.16	177.67	-8.4942
16	50	Unbiased-50k	185.87	176.6	-9.2715
17	60	Biased-50k	186.47	179.85	-6.6136
18	60	Biased-50k	185.51	176.94	-8.5687
19	60	Biased-50k	189.7	182.8	-6.9047
20	60	Biased-50k	186.67	176.96	-9.7163
21	60	Biased-50k	186.36	177.23	-9.1294
24	100	Unbiased-100k	187.48	180.02	-7.4583
25	100	Unbiased-100k	186.57	180.61	-5.9629
26	100	Unbiased-100k	188.69	181.75	-6.9393
27	100	Unbiased-100k	188.91	180.8	-8.1061
28	100	Unbiased-100k	182.9	175.45	-7.4473
29	110	Biased-100k	189.61	182.78	-6.833
30	110	Biased-100k	184.14	174.76	-9.373
31	110	Biased-100k	187.71	179.41	-8.3033
32	110	Biased-100k	187.97	181.59	-6.3756
34	110	Biased-100k	187.84	179.22	-8.6203

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	184.24	185.08	185.82	0.79665	174.54	176.96	178.69	2.1598	-9.7011	-8.1235	-7.1333	1.381
50	185.19	187.01	190.01	1.935	176.6	179.44	182.78	2.4075	-9.2715	-7.5735	-5.3098	1.4977
60	185.51	186.94	189.7	1.6045	176.94	178.76	182.8	2.5677	-9.7163	-8.1865	-6.6136	1.3686
100	182.9	186.91	188.91	2.4318	175.45	179.73	181.75	2.468	-8.1061	-7.1828	-5.9629	0.79778
110	184.14	187.45	189.61	2.0082	174.76	179.55	182.78	3.0664	-9.373	-7.901	-6.3756	1.2563

Device Test: 46.4 MIN_ON_TIME_VIN_5V(OnDeadTime|ON_TIME/SW4/5/5///90.9/634//0///@MIN_ON_TIME_VIN_5V)





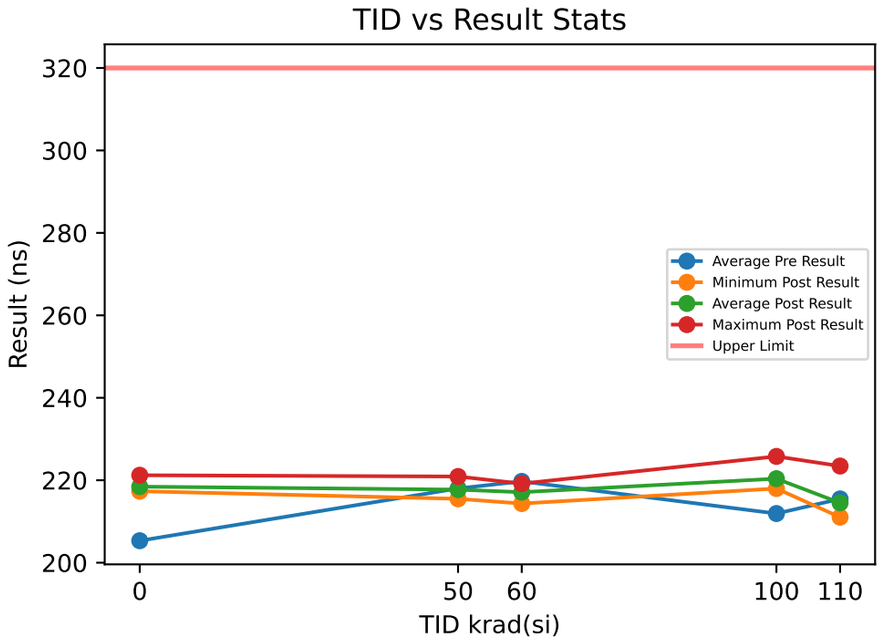
Test Results (Upper Limit = 270.0 (ns))

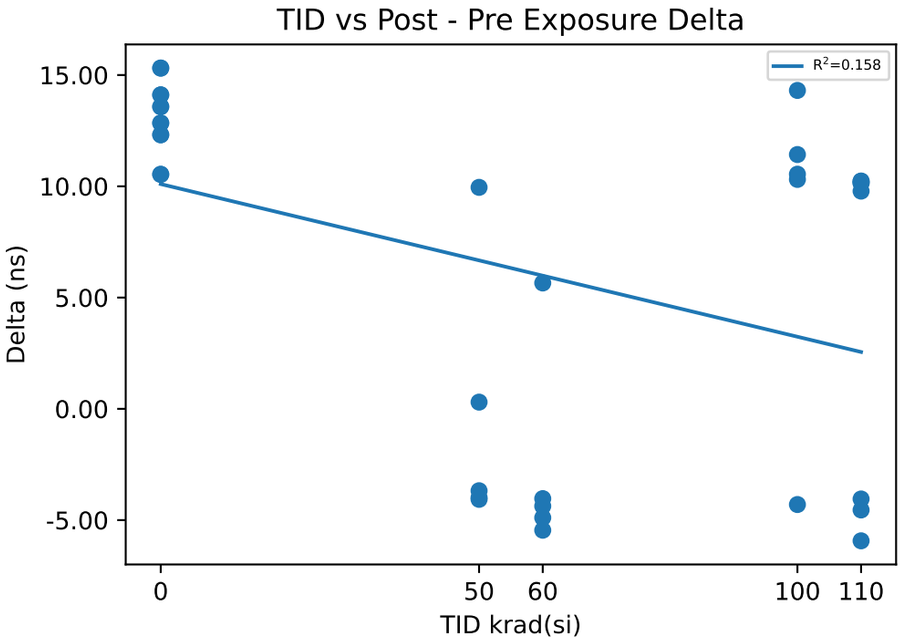
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	186.18	184.15	-2.0279
2	0	CU2	180.15	184.35	4.1997
3	0	CU3	178.86	181.08	2.2251
11	50	Unbiased-50k	181.41	184.22	2.8133
12	50	Unbiased-50k	180.68	181.33	0.6552
13	50	Unbiased-50k	179.1	181.56	2.4591
14	50	Unbiased-50k	181.32	182.28	0.9621
16	50	Unbiased-50k	183.65	181.86	-1.7929
17	60	Biased-50k	181.51	184.37	2.862
18	60	Biased-50k	182.79	182.5	-0.2945
19	60	Biased-50k	182.56	183.76	1.2006
20	60	Biased-50k	185.32	185.01	-0.3131
21	60	Biased-50k	181.47	181.81	0.3407
24	100	Unbiased-100k	181.64	183.51	1.871
25	100	Unbiased-100k	178.21	181.21	3.0064
26	100	Unbiased-100k	180.69	181.99	1.292
27	100	Unbiased-100k	176.14	182.33	6.1909
28	100	Unbiased-100k	177.59	178.7	1.1057
29	110	Biased-100k	178.39	181.24	2.8532
30	110	Biased-100k	184.99	180.33	-4.6667
31	110	Biased-100k	180.04	181.44	1.4013
32	110	Biased-100k	178.93	183.76	4.8312
34	110	Biased-100k	178.08	180.58	2.505

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	178.86	181.73	186.18	3.9087	181.08	183.19	184.35	1.8312	-2.0279	1.4656	4.1997	3.1825
50	179.1	181.23	183.65	1.6396	181.33	182.25	184.22	1.1571	-1.7929	1.0194	2.8133	1.8259
60	181.47	182.73	185.32	1.5666	181.81	183.49	185.01	1.3201	-0.3131	0.75914	2.862	1.3278
100	176.14	178.85	181.64	2.2648	178.7	181.55	183.51	1.7949	1.1057	2.6932	6.1909	2.0911
110	178.08	180.09	184.99	2.8431	180.33	181.47	183.76	1.3615	-4.6667	1.3848	4.8312	3.6024

Device Test: 47.1 MIN_ON_TIME_VIN_7V(OnDeadTime|ON_TIME/SW1/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V)





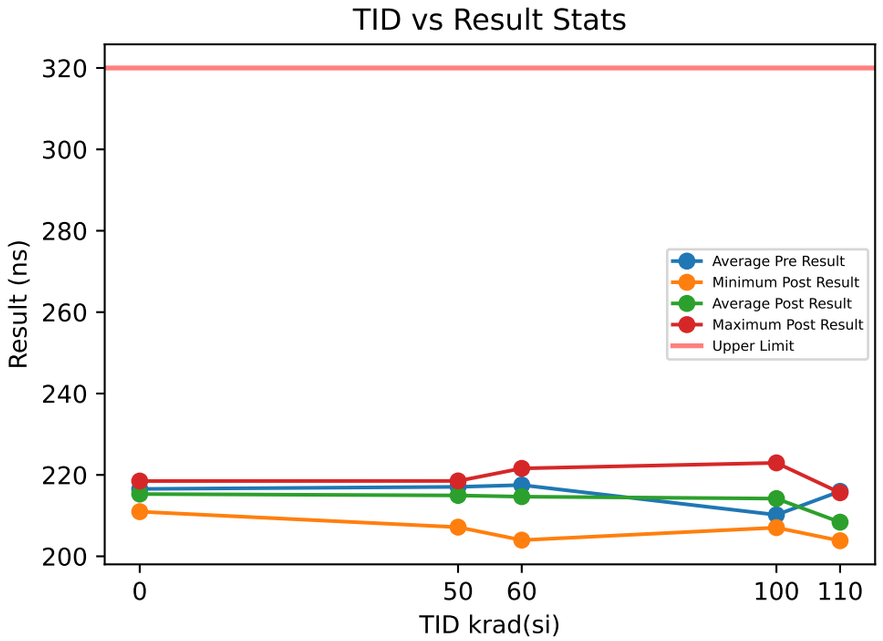
Test Results (Upper Limit = 320.0 (ns))

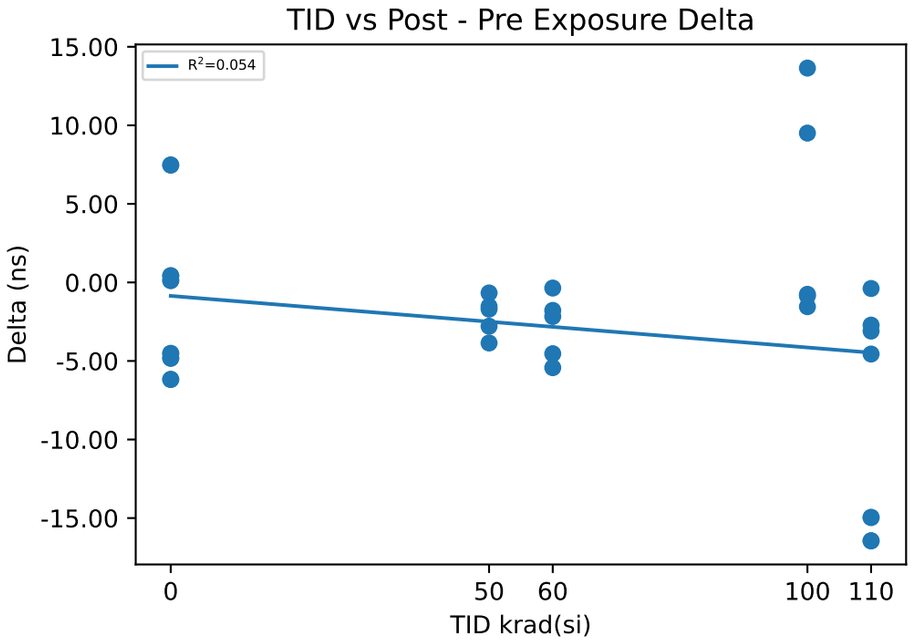
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	207.64	218.17	10.537
2	0	CU2	203.34	217.45	14.108
3	0	CU3	205.02	217.34	12.317
11	50	Unbiased-50k	205.63	215.58	9.9522
12	50	Unbiased-50k	219.17	215.49	-3.6805
13	50	Unbiased-50k	220.61	220.91	0.3012
14	50	Unbiased-50k	220.62	216.56	-4.0666
16	50	Unbiased-50k	224.06	220.07	-3.9858
17	60	Biased-50k	223.56	219.19	-4.3712
18	60	Biased-50k	223.6	218.15	-5.4544
19	60	Biased-50k	219.46	215.42	-4.0347
20	60	Biased-50k	223.3	218.41	-4.8922
21	60	Biased-50k	208.69	214.35	5.6559
24	100	Unbiased-100k	206.57	217.99	11.427
25	100	Unbiased-100k	211.47	225.78	14.308
26	100	Unbiased-100k	207.48	218.02	10.544
27	100	Unbiased-100k	208.14	218.45	10.31
28	100	Unbiased-100k	225.97	221.67	-4.3004
29	110	Biased-100k	208.74	218.53	9.784
30	110	Biased-100k	218	212.07	-5.9308
31	110	Biased-100k	227.99	223.45	-4.544
32	110	Biased-100k	221.72	217.67	-4.0507
34	110	Biased-100k	200.9	211.04	10.146

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	203.34	205.33	207.64	2.1654	217.34	217.65	218.17	0.4542	10.537	12.32	14.108	1.7856
50	205.63	218.02	224.06	7.1549	215.49	217.72	220.91	2.5774	-4.0666	-0.2959	9.9522	6.0139
60	208.69	219.72	223.6	6.4087	214.35	217.1	219.19	2.0941	-5.4544	-2.6193	5.6559	4.6571
100	206.57	211.92	225.97	8.0662	217.99	220.38	225.78	3.3847	-4.3004	8.4577	14.308	7.3075
110	200.9	215.47	227.99	10.722	211.04	216.55	223.45	5.0779	-5.9308	1.081	10.146	8.1404

Device Test: 47.2 MIN_ON_TIME_VIN_7V(OnDeadTime|ON_TIME/SW2/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V)





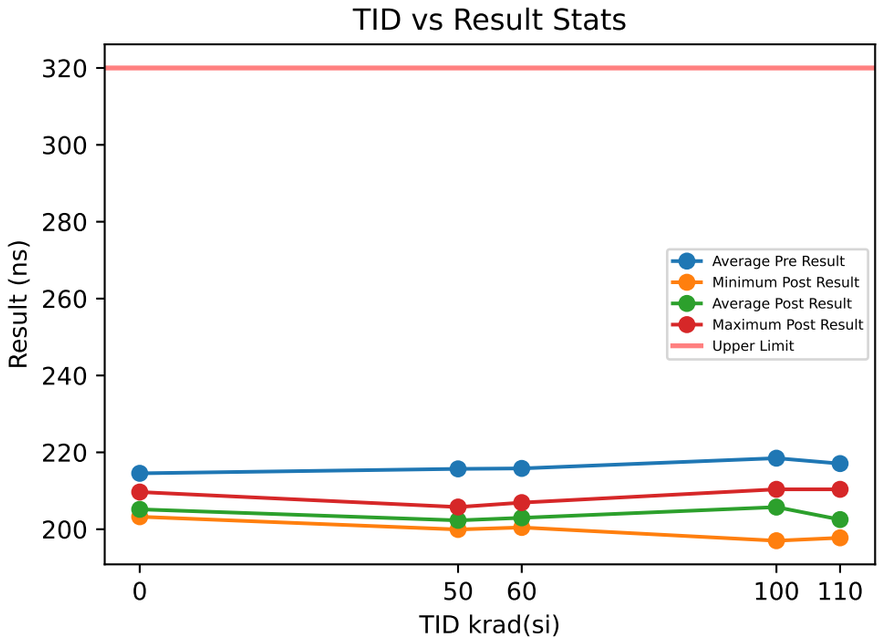
Test Results (Upper Limit = 320.0 (ns))

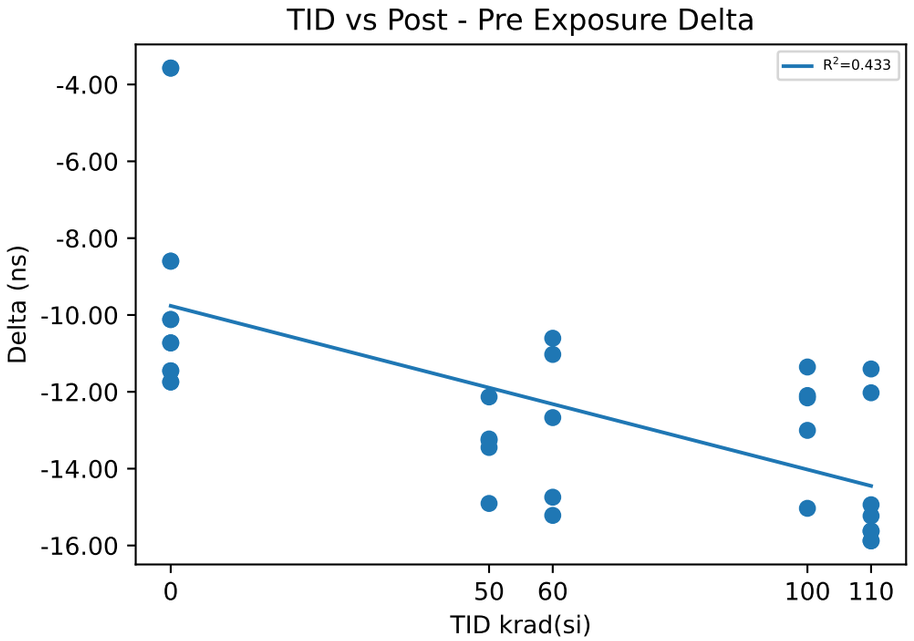
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	220.74	215.92	-4.8226
2	0	CU2	210.54	210.97	0.4244
3	0	CU3	218.37	218.49	0.1208
11	50	Unbiased-50k	211.02	207.16	-3.8557
12	50	Unbiased-50k	216.68	214.98	-1.6987
13	50	Unbiased-50k	219.19	218.52	-0.6715
14	50	Unbiased-50k	218.2	216.67	-1.524
16	50	Unbiased-50k	220.24	217.45	-2.7898
17	60	Biased-50k	218.16	217.81	-0.3585
18	60	Biased-50k	226.14	221.6	-4.537
19	60	Biased-50k	219.17	217.38	-1.7817
20	60	Biased-50k	214.69	212.52	-2.1675
21	60	Biased-50k	209.4	203.98	-5.4259
24	100	Unbiased-100k	209.31	222.96	13.644
25	100	Unbiased-100k	207.8	207.04	-0.7567
26	100	Unbiased-100k	212.55	222.05	9.5057
27	100	Unbiased-100k	211.43	209.89	-1.5445
28	100	Unbiased-100k	209.84	208.98	-0.8575
29	110	Biased-100k	211.66	208.57	-3.098
30	110	Biased-100k	216.01	213.29	-2.7177
31	110	Biased-100k	216.01	215.63	-0.387
32	110	Biased-100k	215.86	211.31	-4.5586
34	110	Biased-100k	220.28	205.32	-14.96

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	210.54	216.55	220.74	5.3384	210.97	215.13	218.49	3.8257	-4.8226	-1.4258	0.4244	2.9456
50	211.02	217.07	220.24	3.627	207.16	214.96	218.52	4.545	-3.8557	-2.1079	-0.6715	1.234
60	209.4	217.51	226.14	6.1512	203.98	214.66	221.6	6.7864	-5.4259	-2.8541	-0.3585	2.0794
100	207.8	210.19	212.55	1.8509	207.04	214.18	222.96	7.6716	-1.5445	3.9982	13.644	7.0761
110	211.66	215.97	220.28	3.0465	205.32	210.82	215.63	4.0244	-14.96	-5.1443	-0.387	5.6877

Device Test: 47.3 MIN_ON_TIME_VIN_7V(OnDeadTime|ON_TIME/SW3/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V)





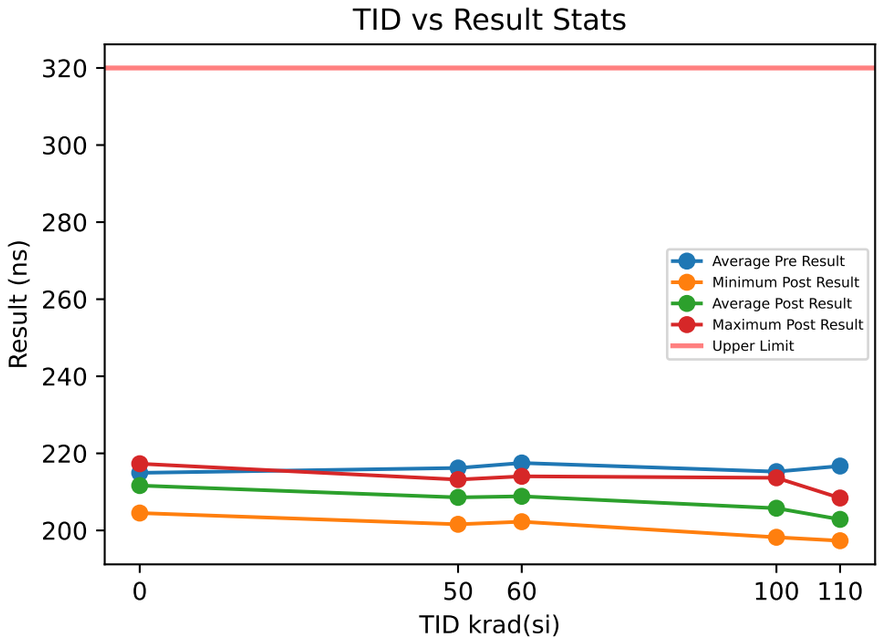
Test Results (Upper Limit = 320.0 (ns))

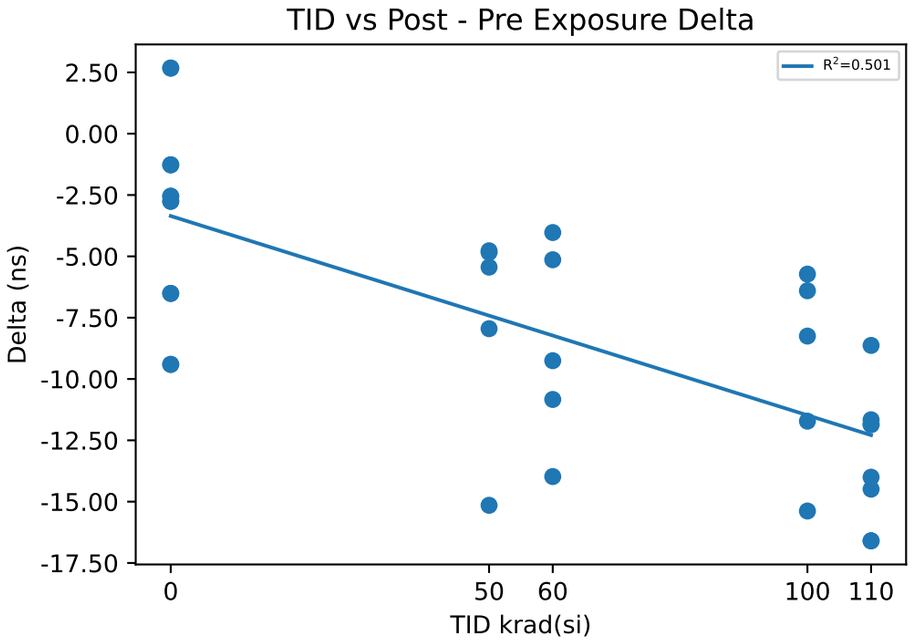
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	213.25	204.65	-8.5991
2	0	CU2	214.7	203.98	-10.726
3	0	CU3	215.69	205.57	-10.118
11	50	Unbiased-50k	216.47	201.56	-14.906
12	50	Unbiased-50k	219	205.78	-13.228
13	50	Unbiased-50k	217.23	203.97	-13.264
14	50	Unbiased-50k	213.39	199.94	-13.448
16	50	Unbiased-50k	212.42	200.29	-12.133
17	60	Biased-50k	215.21	200.46	-14.743
18	60	Biased-50k	211.74	201.14	-10.605
19	60	Biased-50k	222.14	206.92	-15.217
20	60	Biased-50k	213.62	202.59	-11.027
21	60	Biased-50k	216.39	203.72	-12.671
24	100	Unbiased-100k	218.91	207.56	-11.354
25	100	Unbiased-100k	219.67	204.64	-15.033
26	100	Unbiased-100k	221.29	209.19	-12.096
27	100	Unbiased-100k	222.54	210.38	-12.157
28	100	Unbiased-100k	210.02	197.01	-13.004
29	110	Biased-100k	222.41	210.38	-12.025
30	110	Biased-100k	209.17	197.76	-11.405
31	110	Biased-100k	218.33	203.4	-14.94
32	110	Biased-100k	218.38	203.15	-15.23
34	110	Biased-100k	217.11	201.49	-15.626

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	213.25	214.55	215.69	1.2247	203.98	204.73	205.57	0.79843	-10.726	-9.8144	-8.5991	1.0955
50	212.42	215.7	219	2.7368	199.94	202.31	205.78	2.5018	-14.906	-13.396	-12.133	0.9904
60	211.74	215.82	222.14	3.9407	200.46	202.97	206.92	2.5484	-15.217	-12.853	-10.605	2.0964
100	210.02	218.48	222.54	4.9395	197.01	205.76	210.38	5.3418	-15.033	-12.729	-11.354	1.4142
110	209.17	217.08	222.41	4.8535	197.76	203.23	210.38	4.5855	-15.626	-13.845	-11.405	1.9719

Device Test: 47.4 MIN_ON_TIME_VIN_7V(OnDeadTime|ON_TIME/SW4/7/7///90.9/634//0///@MIN_ON_TIME_VIN_7V)





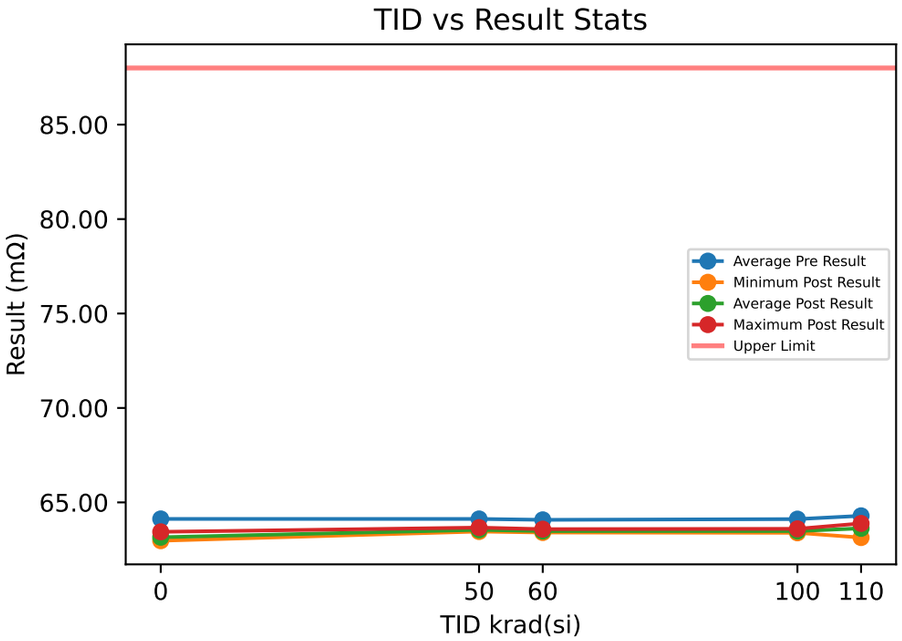
Test Results (Upper Limit = 320.0 (ns))

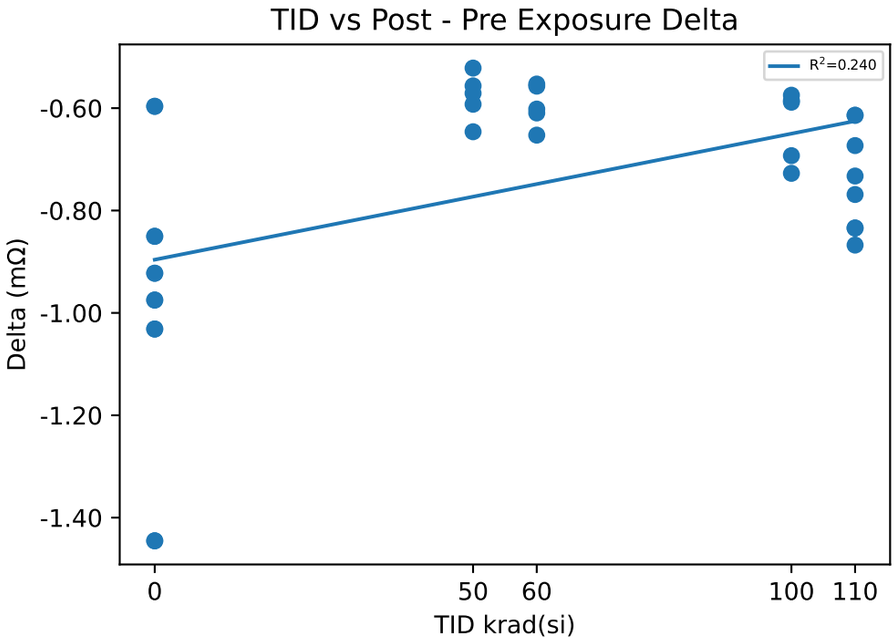
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	218.57	215.82	-2.7554
2	0	CU2	212.34	205.83	-6.5111
3	0	CU3	213.92	211.37	-2.5498
11	50	Unbiased-50k	216.74	201.59	-15.149
12	50	Unbiased-50k	211.01	203.06	-7.9488
13	50	Unbiased-50k	216.88	212.04	-4.8372
14	50	Unbiased-50k	218.64	213.2	-5.4397
16	50	Unbiased-50k	217.75	212.98	-4.7731
17	60	Biased-50k	218.07	214.04	-4.0295
18	60	Biased-50k	220.47	211.22	-9.2542
19	60	Biased-50k	218.55	213.41	-5.1386
20	60	Biased-50k	217.31	203.33	-13.977
21	60	Biased-50k	213.1	202.26	-10.834
24	100	Unbiased-100k	221.9	213.65	-8.2499
25	100	Unbiased-100k	213.6	198.22	-15.382
26	100	Unbiased-100k	215.57	209.84	-5.7242
27	100	Unbiased-100k	214.9	203.18	-11.719
28	100	Unbiased-100k	210.31	203.91	-6.4018
29	110	Biased-100k	211.82	197.33	-14.491
30	110	Biased-100k	222.23	208.23	-14.002
31	110	Biased-100k	217.04	208.41	-8.6307
32	110	Biased-100k	217.4	205.74	-11.662
34	110	Biased-100k	215.04	203.18	-11.857

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	212.34	214.95	218.57	3.2396	205.83	211.01	215.82	5.0025	-6.5111	-3.9388	-2.5498	2.2301
50	211.01	216.2	218.64	3.0026	201.59	208.57	213.2	5.7435	-15.149	-7.6295	-4.7731	4.3987
60	213.1	217.5	220.47	2.7229	202.26	208.85	214.04	5.6377	-13.977	-8.6467	-4.0295	4.0985
100	210.31	215.26	221.9	4.2303	198.22	205.76	213.65	6.0381	-15.382	-9.4953	-5.7242	4.0293
110	211.82	216.71	222.23	3.7997	197.33	204.58	208.41	4.5783	-14.491	-12.129	-8.6307	2.3246

Device Test: 48.1 R_HS_3V_25C(HsRdson|HighSide/SW1/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C)





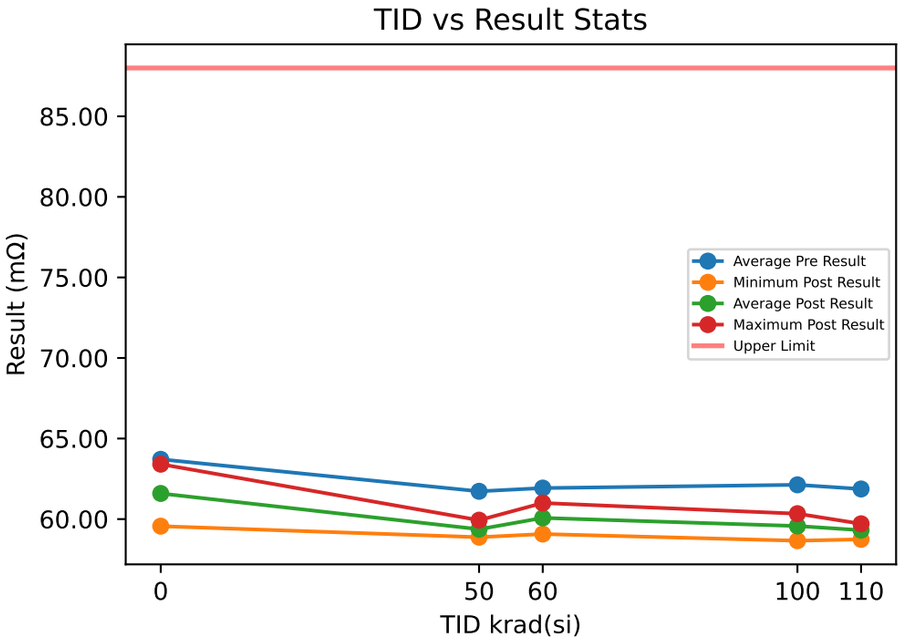
Test Results (Upper Limit = 88.0 (mΩ))

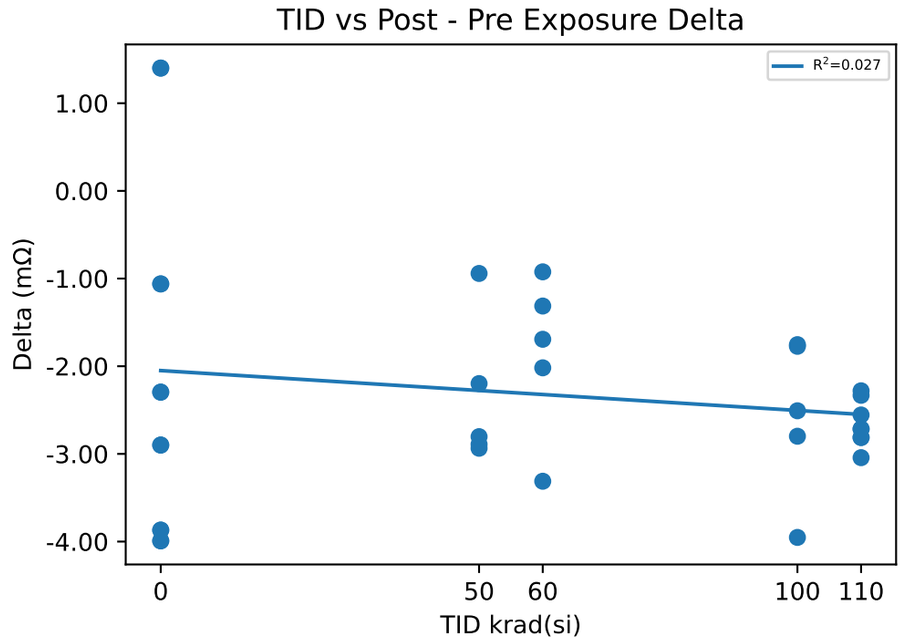
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	64.054	63.131	-0.9225
2	0	CU2	64.416	63.441	-0.9749
3	0	CU3	63.905	63.054	-0.8504
11	50	Unbiased-50k	64.311	63.665	-0.6461
12	50	Unbiased-50k	64.132	63.561	-0.5709
13	50	Unbiased-50k	64.178	63.585	-0.5924
14	50	Unbiased-50k	64.021	63.464	-0.5565
16	50	Unbiased-50k	63.98	63.458	-0.5217
17	60	Biased-50k	64.185	63.583	-0.6018
18	60	Biased-50k	64.125	63.472	-0.6527
19	60	Biased-50k	64.005	63.452	-0.5529
20	60	Biased-50k	63.962	63.406	-0.557
21	60	Biased-50k	64.108	63.498	-0.6094
24	100	Unbiased-100k	64.294	63.601	-0.6928
25	100	Unbiased-100k	64.117	63.39	-0.7273
26	100	Unbiased-100k	64.012	63.427	-0.585
27	100	Unbiased-100k	64.102	63.514	-0.5884
28	100	Unbiased-100k	64.052	63.477	-0.5747
29	110	Biased-100k	64.091	63.418	-0.6731
30	110	Biased-100k	63.907	63.139	-0.7687
31	110	Biased-100k	64.577	63.844	-0.7326
32	110	Biased-100k	64.37	63.503	-0.8675
34	110	Biased-100k	64.499	63.665	-0.8342

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.905	64.125	64.416	0.2632	63.054	63.209	63.441	0.20499	-0.9749	-0.91593	-0.8504	0.062509
50	63.98	64.124	64.311	0.13171	63.458	63.547	63.665	0.087062	-0.6461	-0.57752	-0.5217	0.046169
60	63.962	64.077	64.185	0.091104	63.406	63.482	63.583	0.065903	-0.6527	-0.59476	-0.5529	0.041228
100	64.012	64.115	64.294	0.10803	63.39	63.482	63.601	0.081734	-0.7273	-0.63364	-0.5747	0.07099
110	63.907	64.289	64.577	0.28215	63.139	63.514	63.844	0.26558	-0.8675	-0.77522	-0.6731	0.077913

Device Test: 48.2 R_HS_3V_25C(HsRdson|HighSide/SW2/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C)





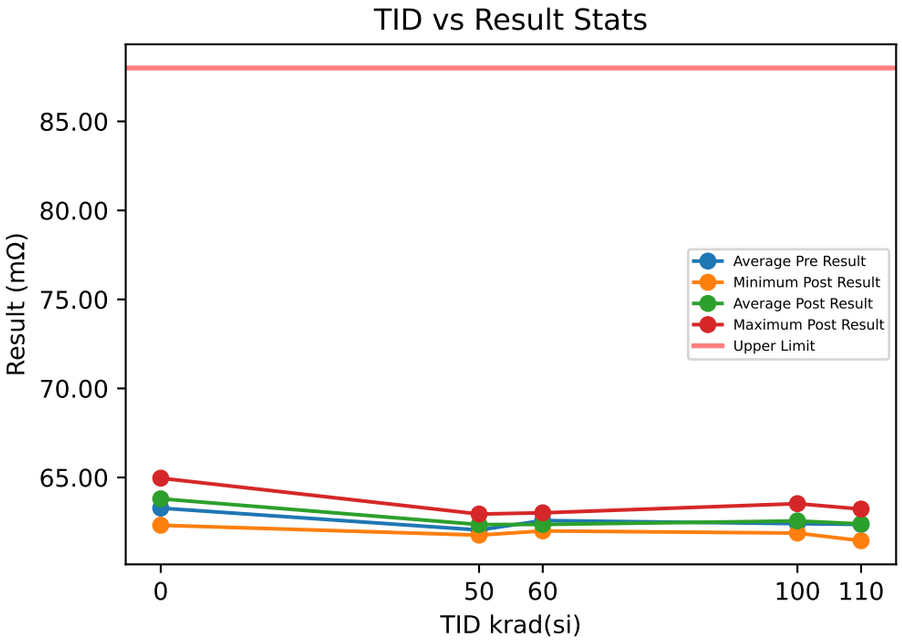
Test Results (Upper Limit = 88.0 (mΩ))

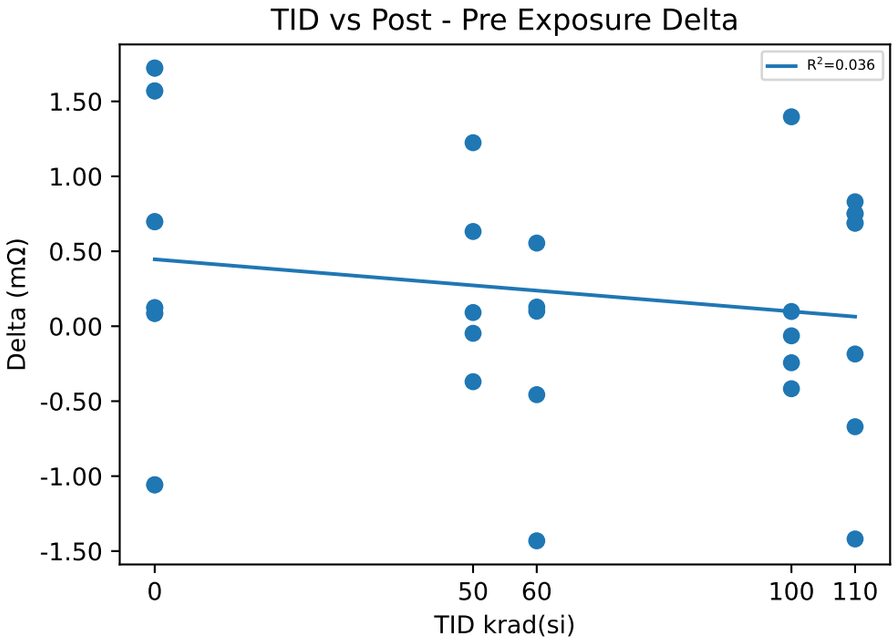
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	65.693	62.794	-2.8991
2	0	CU2	62.007	60.946	-1.0611
3	0	CU3	63.429	59.56	-3.8692
11	50	Unbiased-50k	62.135	59.244	-2.8905
12	50	Unbiased-50k	62.069	59.133	-2.9355
13	50	Unbiased-50k	61.866	59.669	-2.1978
14	50	Unbiased-50k	61.679	58.876	-2.8031
16	50	Unbiased-50k	60.875	59.933	-0.9418
17	60	Biased-50k	62.275	60.582	-1.6926
18	60	Biased-50k	62.384	59.072	-3.3118
19	60	Biased-50k	61.922	60.998	-0.9234
20	60	Biased-50k	61.067	59.754	-1.3134
21	60	Biased-50k	61.979	59.961	-2.0181
24	100	Unbiased-100k	62.02	60.247	-1.7727
25	100	Unbiased-100k	62.09	60.336	-1.7538
26	100	Unbiased-100k	62.329	59.821	-2.5082
27	100	Unbiased-100k	61.587	58.788	-2.7986
28	100	Unbiased-100k	62.61	58.658	-3.9527
29	110	Biased-100k	62.264	59.708	-2.556
30	110	Biased-100k	61.786	58.743	-3.0429
31	110	Biased-100k	61.719	59.387	-2.3317
32	110	Biased-100k	61.433	59.153	-2.2802
34	110	Biased-100k	62.141	59.329	-2.8124

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	62.007	63.71	65.693	1.859	59.56	61.1	62.794	1.6225	-3.8692	-2.6098	-1.0611	1.4262
50	60.875	61.725	62.135	0.50772	58.876	59.371	59.933	0.42472	-2.9355	-2.3537	-0.9418	0.84356
60	61.067	61.925	62.384	0.51776	59.072	60.074	60.998	0.7469	-3.3118	-1.8519	-0.9234	0.91329
100	61.587	62.127	62.61	0.3804	58.658	59.57	60.336	0.79856	-3.9527	-2.5572	-1.7538	0.90402
110	61.433	61.869	62.264	0.33536	58.743	59.264	59.708	0.35362	-3.0429	-2.6046	-2.2802	0.32302

Device Test: 48.3 R_HS_3V_25C(HsRdson|HighSide/SW3/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C)





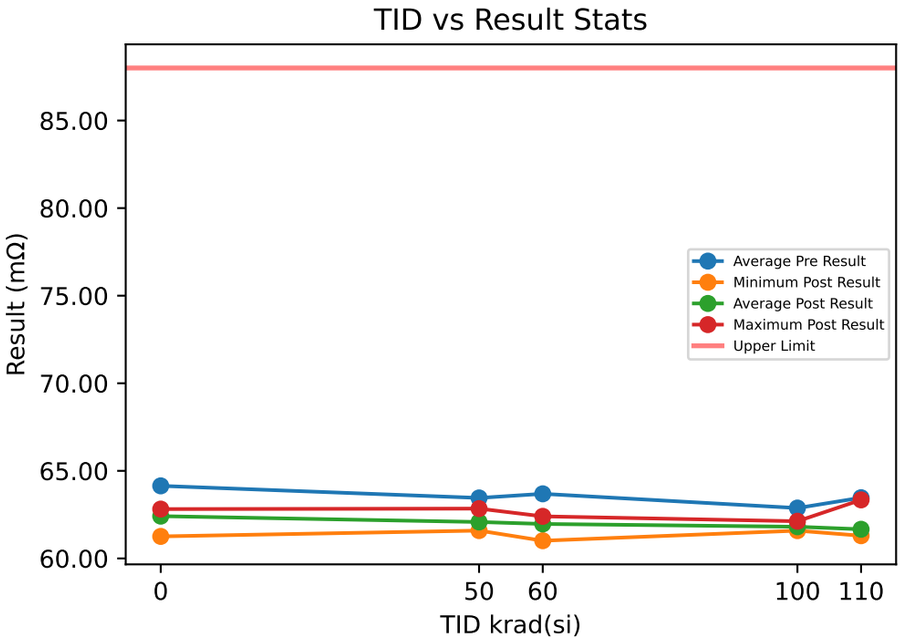
Test Results (Upper Limit = 88.0 (mΩ))

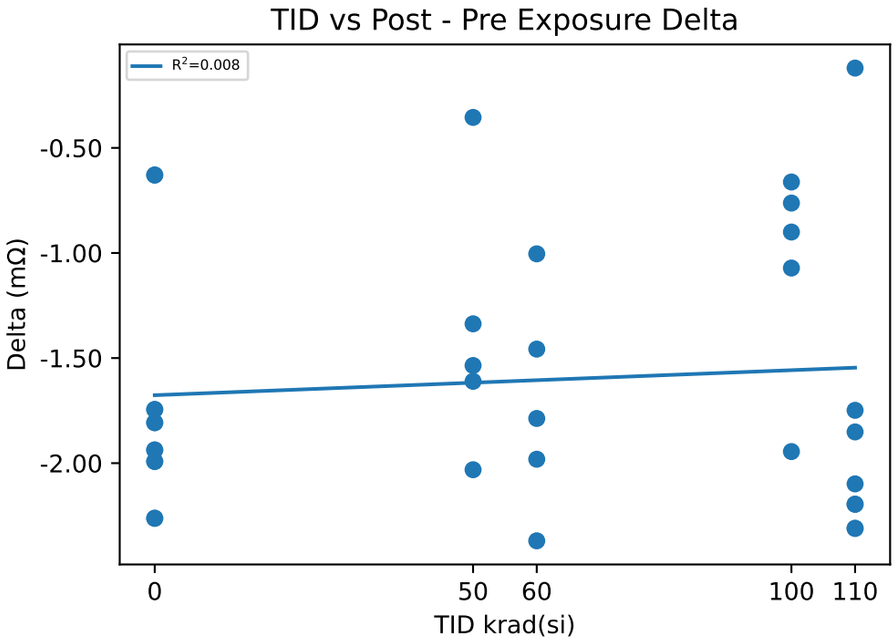
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	63.238	63.361	0.1234
2	0	CU2	63.223	63.309	0.0856
3	0	CU3	63.374	62.316	-1.058
11	50	Unbiased-50k	62.13	61.76	-0.3701
12	50	Unbiased-50k	62.143	62.095	-0.0473
13	50	Unbiased-50k	62.313	62.945	0.6319
14	50	Unbiased-50k	62.063	62.155	0.0914
16	50	Unbiased-50k	61.595	62.819	1.2242
17	60	Biased-50k	62.458	63.013	0.5546
18	60	Biased-50k	63.457	62.025	-1.4316
19	60	Biased-50k	62.343	62.443	0.1002
20	60	Biased-50k	62.452	61.996	-0.4566
21	60	Biased-50k	62.193	62.32	0.1279
24	100	Unbiased-100k	62.131	63.528	1.3971
25	100	Unbiased-100k	62.292	61.876	-0.417
26	100	Unbiased-100k	62.824	62.923	0.0983
27	100	Unbiased-100k	62.555	62.311	-0.2436
28	100	Unbiased-100k	62.217	62.152	-0.0641
29	110	Biased-100k	62.395	63.225	0.8302
30	110	Biased-100k	62.117	61.446	-0.6705
31	110	Biased-100k	62.417	62.232	-0.1853
32	110	Biased-100k	62.916	61.496	-1.4193
34	110	Biased-100k	61.961	62.648	0.6879

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.223	63.278	63.374	0.083089	62.316	62.995	63.361	0.58899	-1.058	-0.283	0.1234	0.67144
50	61.595	62.049	62.313	0.27001	61.76	62.355	62.945	0.50627	-0.3701	0.30602	1.2242	0.62795
60	62.193	62.58	63.457	0.50154	61.996	62.359	63.013	0.41209	-1.4316	-0.2211	0.5546	0.76608
100	62.131	62.404	62.824	0.28355	61.876	62.558	63.528	0.66422	-0.417	0.15414	1.3971	0.72113
110	61.961	62.361	62.916	0.36472	61.446	62.21	63.225	0.76094	-1.4193	-0.1514	0.8302	0.94156

Device Test: 48.4 R_HS_3V_25C(HsRdson|HighSide/SW4/3/3/0.5//90.9/634//1.8///@R_HS_3V_25C)





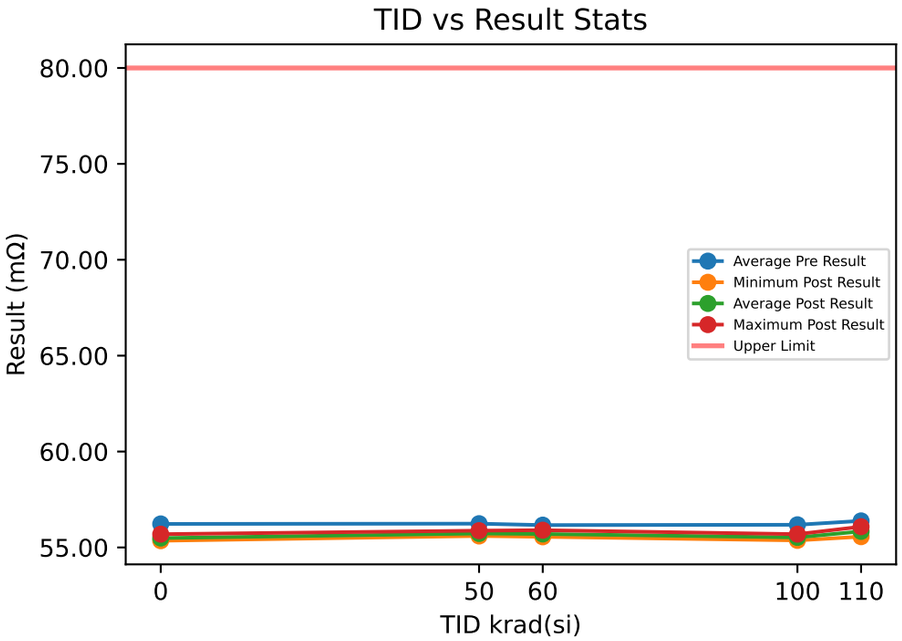
Test Results (Upper Limit = 88.0 (mΩ))

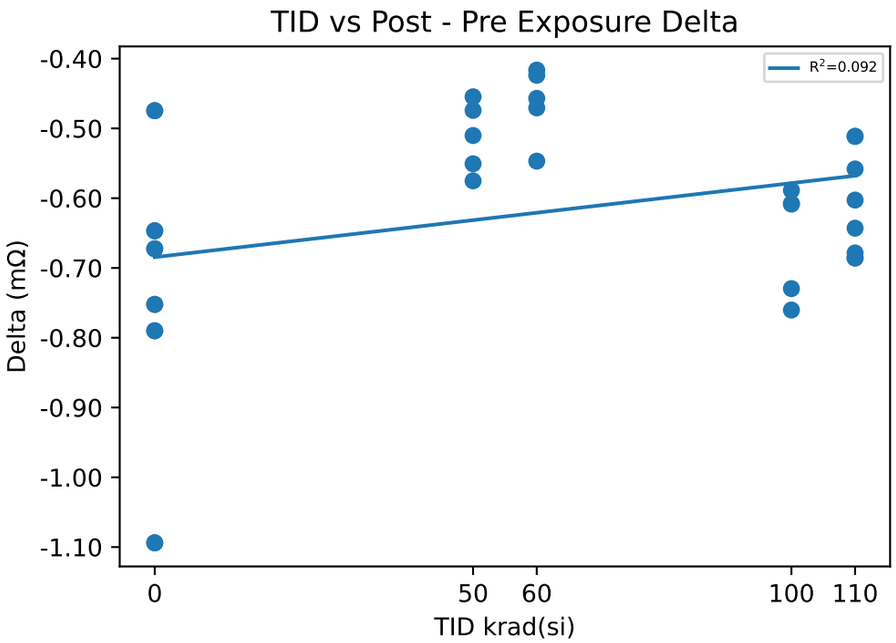
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	64.802	62.81	-1.9919
2	0	CU2	63.002	62.373	-0.6292
3	0	CU3	64.624	62.816	-1.8073
11	50	Unbiased-50k	63.612	62.077	-1.5354
12	50	Unbiased-50k	63.977	61.946	-2.0313
13	50	Unbiased-50k	63.199	61.589	-1.6106
14	50	Unbiased-50k	63.198	62.843	-0.355
16	50	Unbiased-50k	63.279	61.942	-1.3371
17	60	Biased-50k	64.281	62.3	-1.9813
18	60	Biased-50k	64.16	61.791	-2.3695
19	60	Biased-50k	63.406	62.402	-1.0041
20	60	Biased-50k	62.798	61.011	-1.7874
21	60	Biased-50k	63.795	62.338	-1.4574
24	100	Unbiased-100k	63.53	61.585	-1.9449
25	100	Unbiased-100k	62.785	62.122	-0.6623
26	100	Unbiased-100k	62.648	61.885	-0.7626
27	100	Unbiased-100k	62.681	61.609	-1.0717
28	100	Unbiased-100k	62.739	61.839	-0.9004
29	110	Biased-100k	63.551	61.699	-1.8514
30	110	Biased-100k	63.563	61.465	-2.0986
31	110	Biased-100k	63.142	61.394	-1.7486
32	110	Biased-100k	63.463	63.342	-0.1203
34	110	Biased-100k	63.606	61.296	-2.3102

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.002	64.143	64.802	0.99187	62.373	62.666	62.816	0.2544	-1.9919	-1.4761	-0.6292	0.73925
50	63.198	63.453	63.977	0.33889	61.589	62.079	62.843	0.464	-2.0313	-1.3739	-0.355	0.62326
60	62.798	63.688	64.281	0.60385	61.011	61.968	62.402	0.58819	-2.3695	-1.7199	-1.0041	0.51869
100	62.648	62.877	63.53	0.36889	61.585	61.808	62.122	0.22082	-1.9449	-1.0684	-0.6623	0.51355
110	63.142	63.465	63.606	0.18784	61.296	61.839	63.342	0.85334	-2.3102	-1.6258	-0.1203	0.86955

Device Test: 49.1 R_HS_5V_25C(HsRdson|HighSide/SW1/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C)





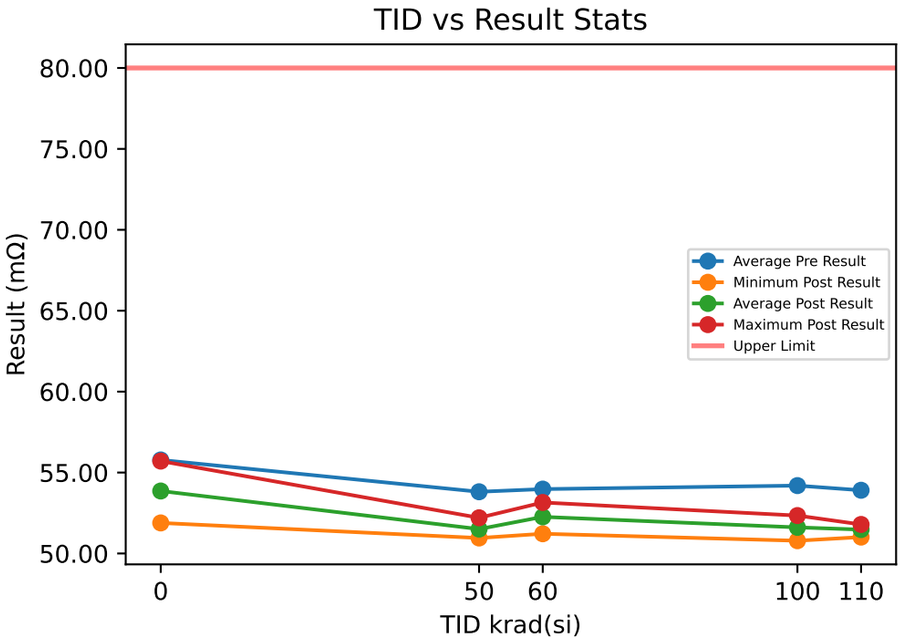
Test Results (Upper Limit = 80.0 (mΩ))

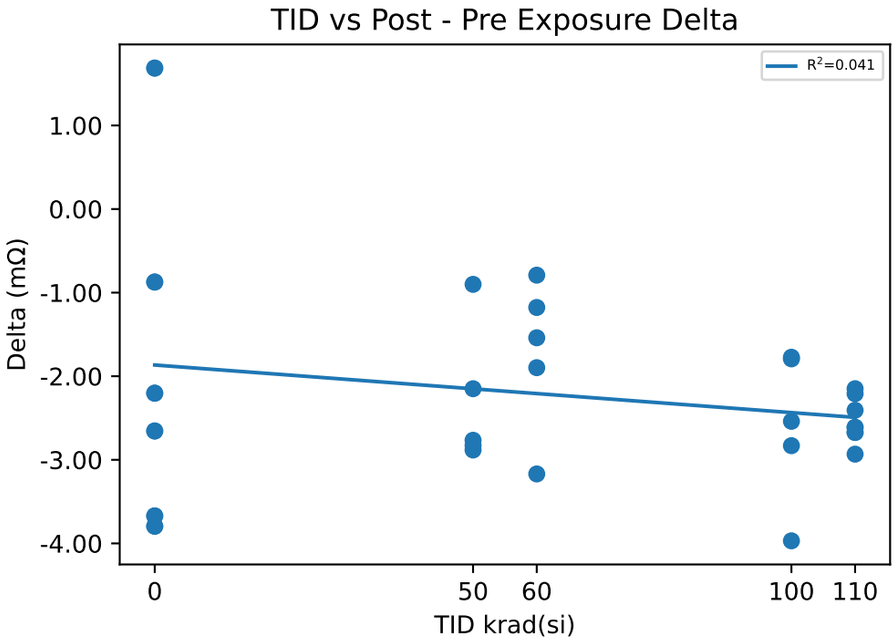
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	56.173	55.501	-0.6725
2	0	CU2	56.444	55.692	-0.7522
3	0	CU3	56.062	55.416	-0.6467
11	50	Unbiased-50k	56.45	55.875	-0.5752
12	50	Unbiased-50k	56.273	55.722	-0.5507
13	50	Unbiased-50k	56.169	55.659	-0.5102
14	50	Unbiased-50k	56.071	55.597	-0.4741
16	50	Unbiased-50k	56.232	55.777	-0.4547
17	60	Biased-50k	56.356	55.899	-0.4569
18	60	Biased-50k	56.174	55.627	-0.5469
19	60	Biased-50k	56.036	55.62	-0.4164
20	60	Biased-50k	55.978	55.554	-0.4239
21	60	Biased-50k	56.278	55.807	-0.4706
24	100	Unbiased-100k	56.453	55.693	-0.7603
25	100	Unbiased-100k	56.097	55.367	-0.7296
26	100	Unbiased-100k	56.024	55.416	-0.6085
27	100	Unbiased-100k	56.139	55.532	-0.6077
28	100	Unbiased-100k	56.194	55.605	-0.5887
29	110	Biased-100k	56.134	55.576	-0.5581
30	110	Biased-100k	56.204	55.561	-0.643
31	110	Biased-100k	56.684	56.081	-0.6027
32	110	Biased-100k	56.351	55.673	-0.6785
34	110	Biased-100k	56.549	55.864	-0.6857

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	56.062	56.227	56.444	0.19639	55.416	55.536	55.692	0.14149	-0.7522	-0.69047	-0.6467	0.054997
50	56.071	56.239	56.45	0.14055	55.597	55.726	55.875	0.10729	-0.5752	-0.51298	-0.4547	0.050522
60	55.978	56.165	56.356	0.15875	55.554	55.702	55.899	0.145	-0.5469	-0.46294	-0.4164	0.052045
100	56.024	56.182	56.453	0.16388	55.367	55.523	55.693	0.13356	-0.7603	-0.65896	-0.5887	0.07964
110	56.134	56.384	56.684	0.23098	55.561	55.751	56.081	0.22066	-0.6857	-0.6336	-0.5581	0.053558

Device Test: 49.2 R_HS_5V_25C(HsRdson|HighSide/SW2/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C)





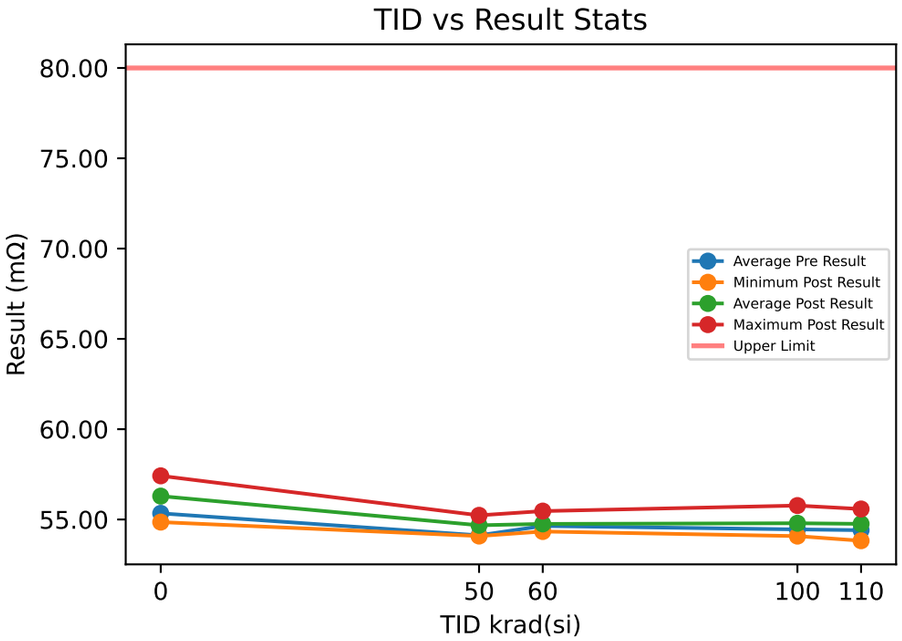
Test Results (Upper Limit = 80.0 (mΩ))

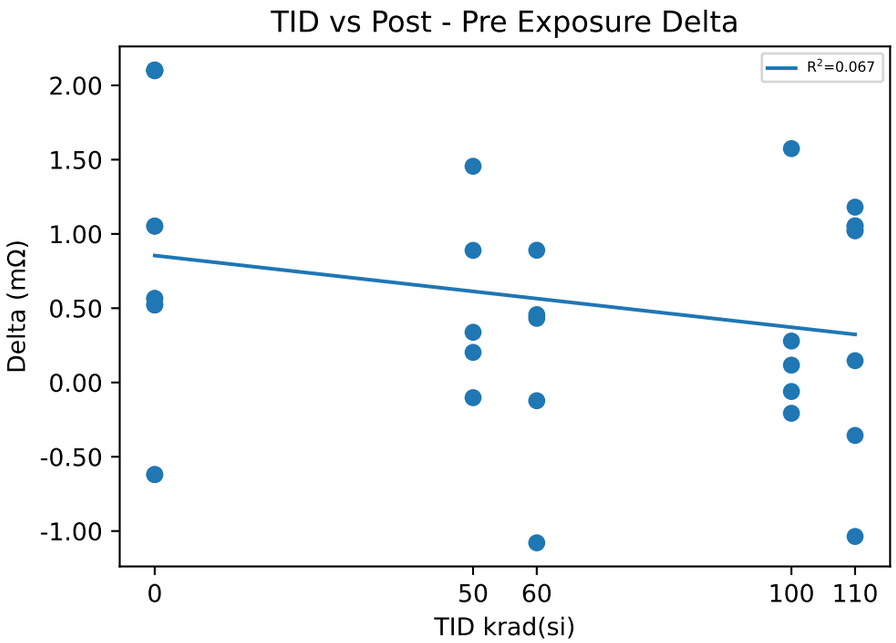
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	57.755	55.099	-2.6551
2	0	CU2	54.021	53.148	-0.8732
3	0	CU3	55.558	51.887	-3.671
11	50	Unbiased-50k	54.226	51.397	-2.8292
12	50	Unbiased-50k	54.161	51.279	-2.8824
13	50	Unbiased-50k	53.846	51.696	-2.1495
14	50	Unbiased-50k	53.722	50.956	-2.766
16	50	Unbiased-50k	53.106	52.205	-0.9008
17	60	Biased-50k	54.422	52.882	-1.54
18	60	Biased-50k	54.387	51.218	-3.1691
19	60	Biased-50k	53.941	53.151	-0.7909
20	60	Biased-50k	53.05	51.872	-1.1775
21	60	Biased-50k	54.086	52.188	-1.8976
24	100	Unbiased-100k	54.134	52.342	-1.7922
25	100	Unbiased-100k	54.085	52.312	-1.7729
26	100	Unbiased-100k	54.351	51.812	-2.5394
27	100	Unbiased-100k	53.638	50.807	-2.8308
28	100	Unbiased-100k	54.757	50.788	-3.9691
29	110	Biased-100k	54.2	51.793	-2.4071
30	110	Biased-100k	53.944	51.012	-2.9323
31	110	Biased-100k	53.778	51.569	-2.2093
32	110	Biased-100k	53.424	51.275	-2.1492
34	110	Biased-100k	54.182	51.509	-2.6727

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	54.021	55.778	57.755	1.8764	51.887	53.378	55.099	1.6186	-3.671	-2.3998	-0.8732	1.4163
50	53.106	53.812	54.226	0.44751	50.956	51.507	52.205	0.47186	-2.8824	-2.3056	-0.9008	0.83914
60	53.05	53.977	54.422	0.55654	51.218	52.262	53.151	0.77789	-3.1691	-1.715	-0.7909	0.91121
100	53.638	54.193	54.757	0.40805	50.788	51.612	52.342	0.77318	-3.9691	-2.5809	-1.7729	0.90363
110	53.424	53.906	54.2	0.32121	51.012	51.432	51.793	0.29849	-2.9323	-2.4741	-2.1492	0.3277

Device Test: 49.3 R_HS_5V_25C(HsRdson|HighSide/SW3/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C)





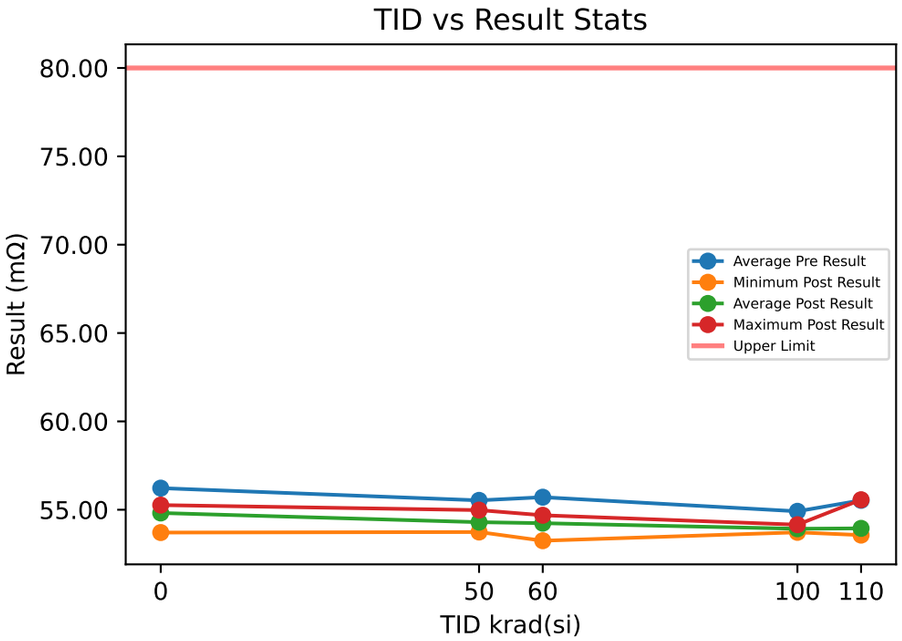
Test Results (Upper Limit = 80.0 (mΩ))

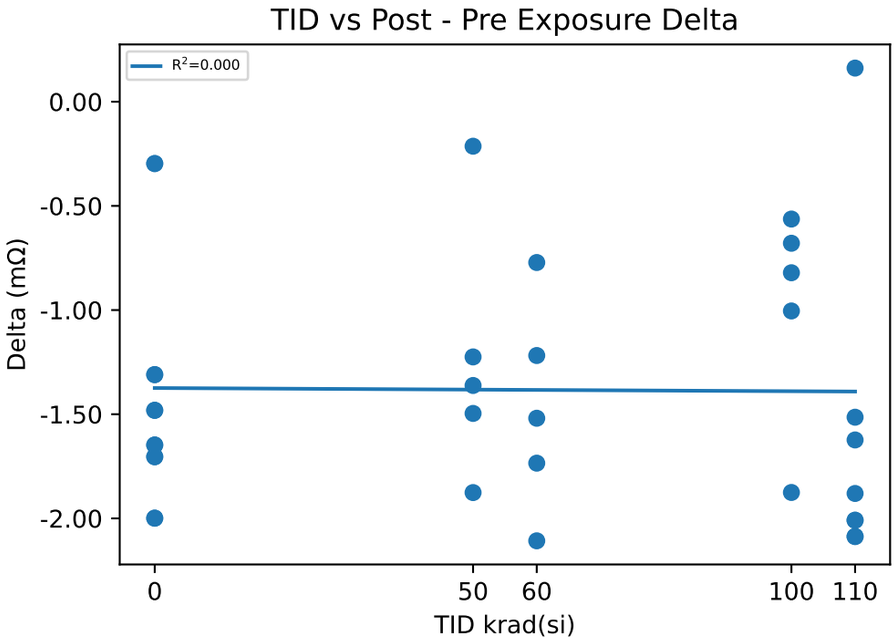
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	55.319	55.884	0.5653
2	0	CU2	55.227	55.749	0.5219
3	0	CU3	55.475	54.855	-0.6199
11	50	Unbiased-50k	54.187	54.084	-0.1022
12	50	Unbiased-50k	54.2	54.403	0.2026
13	50	Unbiased-50k	54.333	55.222	0.8892
14	50	Unbiased-50k	54.121	54.459	0.338
16	50	Unbiased-50k	53.775	55.231	1.4554
17	60	Biased-50k	54.575	55.465	0.8902
18	60	Biased-50k	55.446	54.367	-1.0792
19	60	Biased-50k	54.398	54.829	0.4318
20	60	Biased-50k	54.458	54.335	-0.1228
21	60	Biased-50k	54.327	54.783	0.4567
24	100	Unbiased-100k	54.197	55.771	1.5743
25	100	Unbiased-100k	54.288	54.08	-0.2073
26	100	Unbiased-100k	54.84	55.119	0.279
27	100	Unbiased-100k	54.581	54.52	-0.0607
28	100	Unbiased-100k	54.352	54.468	0.1169
29	110	Biased-100k	54.4	55.581	1.1802
30	110	Biased-100k	54.299	53.943	-0.3566
31	110	Biased-100k	54.5	54.646	0.1467
32	110	Biased-100k	54.861	53.825	-1.0365
34	110	Biased-100k	53.98	55.002	1.0222

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	55.227	55.34	55.475	0.1254	54.855	55.496	55.884	0.55895	-0.6199	0.15577	0.5653	0.6721
50	53.775	54.123	54.333	0.20914	54.084	54.68	55.231	0.51897	-0.1022	0.5566	1.4554	0.61757
60	54.327	54.641	55.446	0.45931	54.335	54.756	55.465	0.45758	-1.0792	0.11534	0.8902	0.75841
100	54.197	54.451	54.84	0.25952	54.08	54.792	55.771	0.66151	-0.2073	0.34044	1.5743	0.71363
110	53.98	54.408	54.861	0.31986	53.825	54.599	55.581	0.7346	-1.0365	0.1912	1.1802	0.93247

Device Test: 49.4 R_HS_5V_25C(HsRdson|HighSide/SW4/5/5/0.5//90.9/634//1.8///@R_HS_5V_25C)





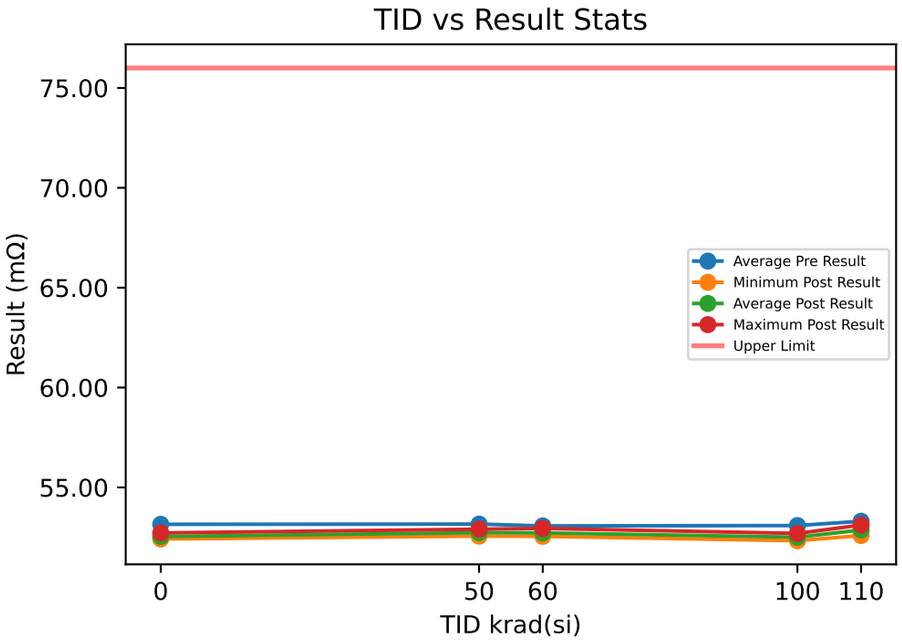
Test Results (Upper Limit = 80.0 (mΩ))

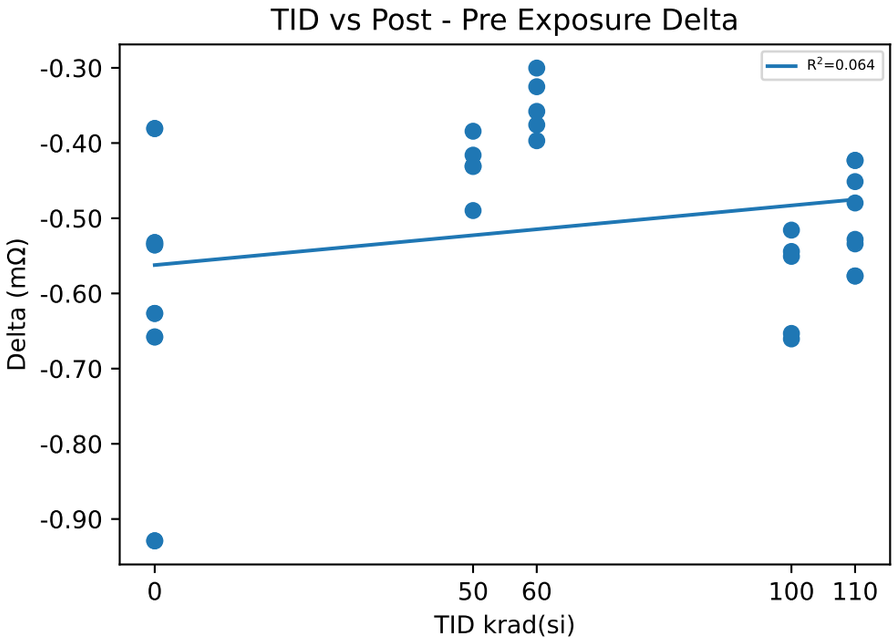
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	56.906	55.258	-1.6478
2	0	CU2	55.019	54.722	-0.2968
3	0	CU3	56.745	55.263	-1.4812
11	50	Unbiased-50k	55.697	54.335	-1.362
12	50	Unbiased-50k	56.003	54.127	-1.8761
13	50	Unbiased-50k	55.234	53.738	-1.4962
14	50	Unbiased-50k	55.192	54.979	-0.2135
16	50	Unbiased-50k	55.523	54.299	-1.2249
17	60	Biased-50k	56.348	54.613	-1.7349
18	60	Biased-50k	56.126	54.018	-2.1077
19	60	Biased-50k	55.403	54.631	-0.7718
20	60	Biased-50k	54.766	53.247	-1.5193
21	60	Biased-50k	55.906	54.688	-1.2182
24	100	Unbiased-100k	55.615	53.74	-1.8756
25	100	Unbiased-100k	54.717	54.154	-0.5631
26	100	Unbiased-100k	54.628	53.949	-0.6793
27	100	Unbiased-100k	54.725	53.721	-1.0043
28	100	Unbiased-100k	54.873	54.052	-0.8209
29	110	Biased-100k	55.578	53.955	-1.6235
30	110	Biased-100k	55.791	53.911	-1.8804
31	110	Biased-100k	55.233	53.719	-1.5144
32	110	Biased-100k	55.404	55.566	0.1616
34	110	Biased-100k	55.652	53.565	-2.087

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	55.019	56.223	56.906	1.0461	54.722	55.081	55.263	0.31106	-1.6478	-1.1419	-0.2968	0.73663
50	55.192	55.53	56.003	0.33661	53.738	54.295	54.979	0.44941	-1.8761	-1.2345	-0.2135	0.62027
60	54.766	55.71	56.348	0.63327	53.247	54.239	54.688	0.61816	-2.1077	-1.4704	-0.7718	0.50748
100	54.628	54.912	55.615	0.40304	53.721	53.923	54.154	0.19028	-1.8756	-0.98864	-0.5631	0.52246
110	55.233	55.532	55.791	0.21752	53.565	54.143	55.566	0.8107	-2.087	-1.3887	0.1616	0.89495

Device Test: 50.1 R_HS_7V_25C(HsRdson|HighSide/SW1/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C)





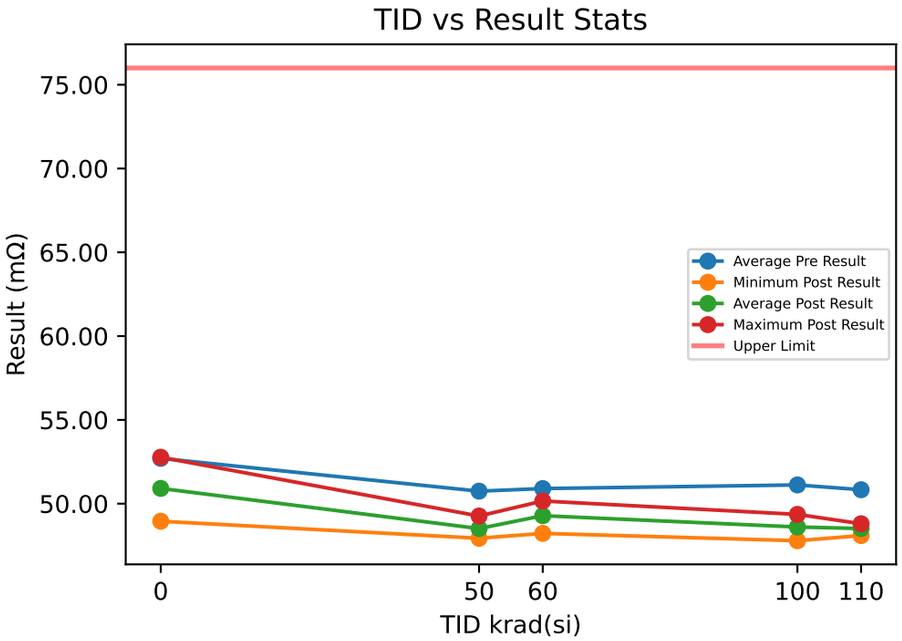
Test Results (Upper Limit = 76.0 (mΩ))

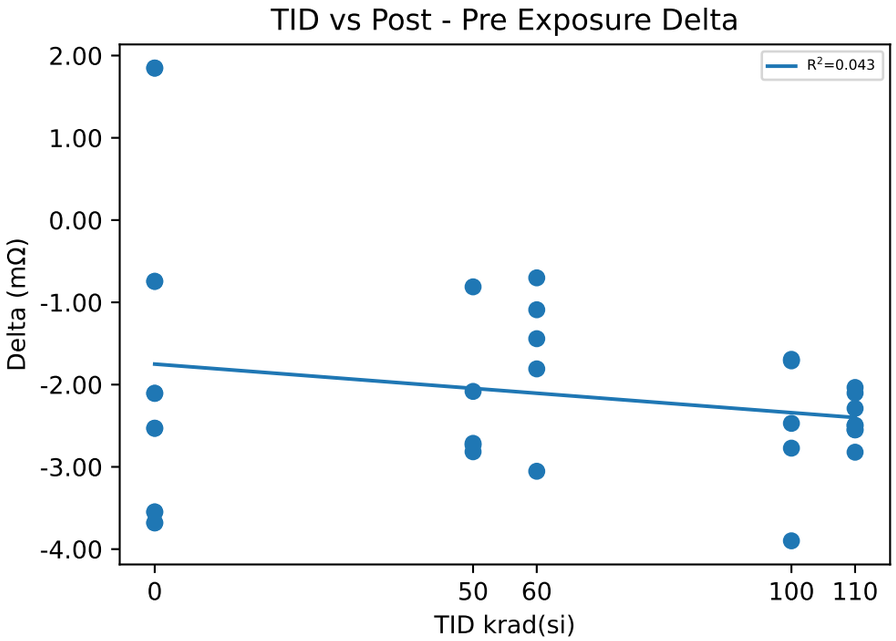
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	53.1	52.565	-0.5355
2	0	CU2	53.347	52.721	-0.6266
3	0	CU3	53.01	52.478	-0.5324
11	50	Unbiased-50k	53.396	52.906	-0.4898
12	50	Unbiased-50k	53.161	52.729	-0.4312
13	50	Unbiased-50k	53.068	52.638	-0.4306
14	50	Unbiased-50k	52.976	52.56	-0.4161
16	50	Unbiased-50k	53.213	52.829	-0.3843
17	60	Biased-50k	53.305	52.947	-0.3579
18	60	Biased-50k	53.024	52.627	-0.3969
19	60	Biased-50k	52.927	52.627	-0.3003
20	60	Biased-50k	52.875	52.55	-0.3251
21	60	Biased-50k	53.229	52.853	-0.3758
24	100	Unbiased-100k	53.349	52.696	-0.6532
25	100	Unbiased-100k	52.991	52.331	-0.6605
26	100	Unbiased-100k	52.931	52.38	-0.5507
27	100	Unbiased-100k	53.049	52.505	-0.5442
28	100	Unbiased-100k	53.131	52.616	-0.5158
29	110	Biased-100k	53.042	52.591	-0.4513
30	110	Biased-100k	53.197	52.669	-0.5281
31	110	Biased-100k	53.594	53.115	-0.4797
32	110	Biased-100k	53.232	52.698	-0.5341
34	110	Biased-100k	53.466	52.889	-0.5768

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	53.01	53.153	53.347	0.17464	52.478	52.588	52.721	0.12319	-0.6266	-0.56483	-0.5324	0.053514
50	52.976	53.163	53.396	0.15883	52.56	52.732	52.906	0.13997	-0.4898	-0.4304	-0.3843	0.038271
60	52.875	53.072	53.305	0.18797	52.55	52.721	52.947	0.17016	-0.3969	-0.3512	-0.3003	0.038764
100	52.931	53.09	53.349	0.16244	52.331	52.505	52.696	0.15382	-0.6605	-0.58488	-0.5158	0.067047
110	53.042	53.306	53.594	0.22117	52.591	52.792	53.115	0.21094	-0.5768	-0.514	-0.4513	0.049129

Device Test: 50.2 R_HS_7V_25C(HsRdson|HighSide/SW2/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C)





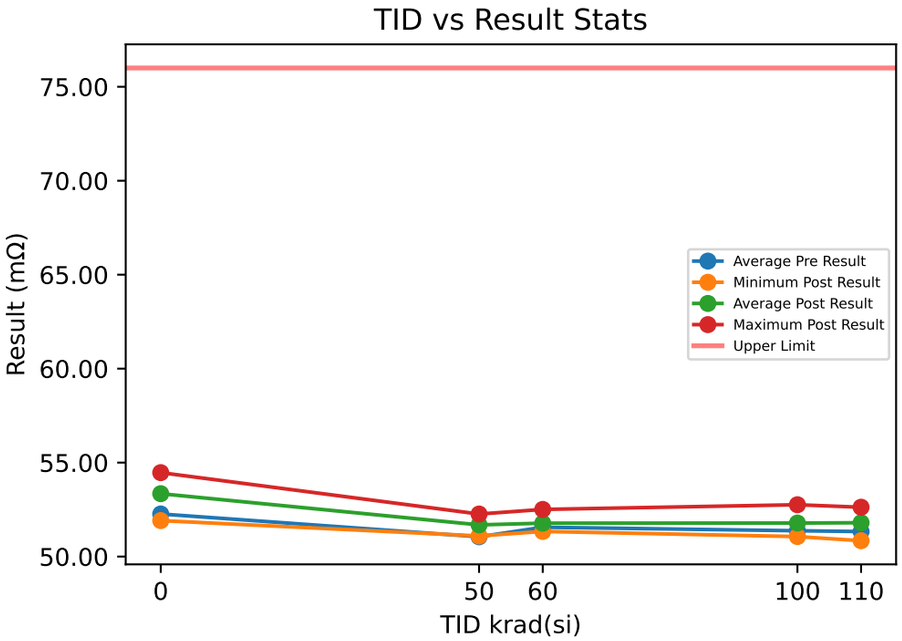
Test Results (Upper Limit = 76.0 (mΩ))

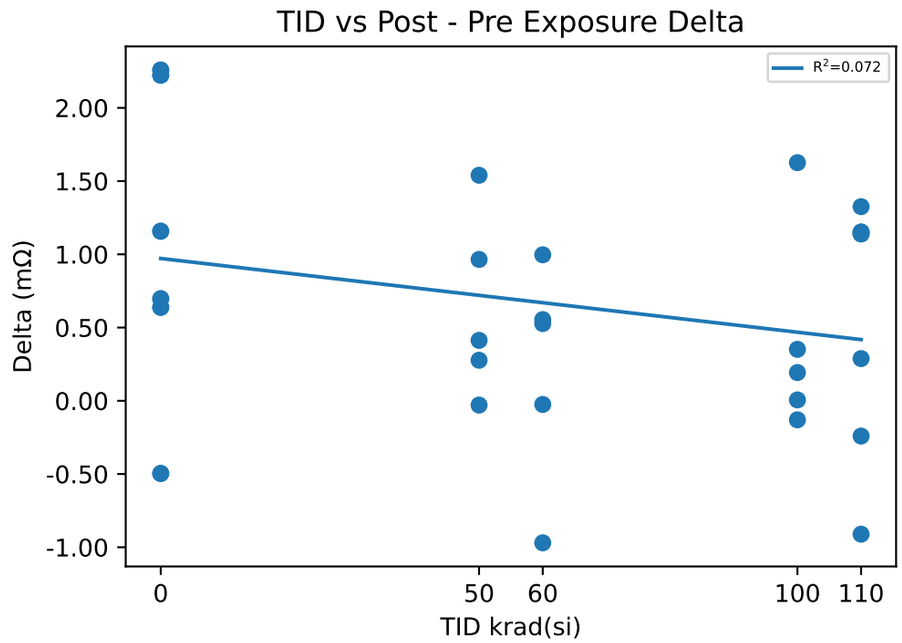
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	54.691	52.16	-2.5307
2	0	CU2	50.922	50.178	-0.7448
3	0	CU3	52.499	48.951	-3.5483
11	50	Unbiased-50k	51.148	48.414	-2.7342
12	50	Unbiased-50k	51.111	48.294	-2.8162
13	50	Unbiased-50k	50.748	48.665	-2.0828
14	50	Unbiased-50k	50.65	47.936	-2.7144
16	50	Unbiased-50k	50.075	49.263	-0.8116
17	60	Biased-50k	51.373	49.931	-1.442
18	60	Biased-50k	51.281	48.227	-3.0533
19	60	Biased-50k	50.861	50.159	-0.7022
20	60	Biased-50k	49.964	48.874	-1.0901
21	60	Biased-50k	51.031	49.222	-1.8089
24	100	Unbiased-100k	51.072	49.361	-1.7115
25	100	Unbiased-100k	50.986	49.293	-1.693
26	100	Unbiased-100k	51.255	48.784	-2.4712
27	100	Unbiased-100k	50.562	47.789	-2.7725
28	100	Unbiased-100k	51.715	47.816	-3.899
29	110	Biased-100k	51.091	48.801	-2.2897
30	110	Biased-100k	50.918	48.096	-2.8216
31	110	Biased-100k	50.71	48.607	-2.1027
32	110	Biased-100k	50.339	48.304	-2.0351
34	110	Biased-100k	51.101	48.551	-2.5495

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.922	52.704	54.691	1.8924	48.951	50.429	52.16	1.6191	-3.5483	-2.2746	-0.7448	1.4192
50	50.075	50.746	51.148	0.43429	47.936	48.514	49.263	0.49405	-2.8162	-2.2318	-0.8116	0.84646
60	49.964	50.902	51.373	0.56197	48.227	49.283	50.159	0.7863	-3.0533	-1.6193	-0.7022	0.90068
100	50.562	51.118	51.715	0.41956	47.789	48.609	49.361	0.769	-3.899	-2.5094	-1.693	0.90896
110	50.339	50.832	51.101	0.318	48.096	48.472	48.801	0.27486	-2.8216	-2.3597	-2.0351	0.32622

Device Test: 50.3 R_HS_7V_25C(HsRdson|HighSide/SW3/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C)





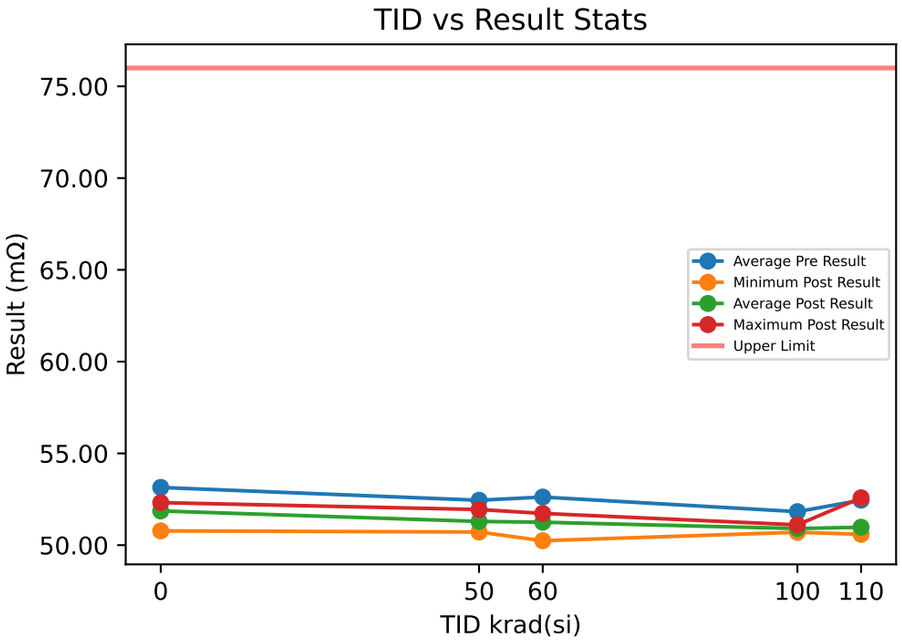
Test Results (Upper Limit = 76.0 (mΩ))

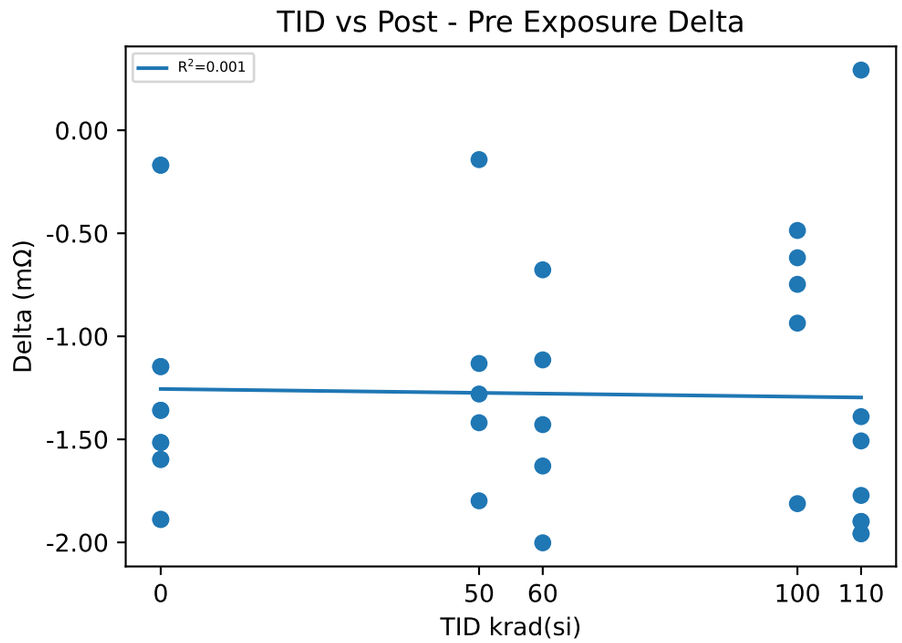
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	52.243	52.94	0.6966
2	0	CU2	52.145	52.783	0.6382
3	0	CU3	52.41	51.914	-0.4962
11	50	Unbiased-50k	51.127	51.097	-0.0293
12	50	Unbiased-50k	51.129	51.405	0.2768
13	50	Unbiased-50k	51.245	52.211	0.965
14	50	Unbiased-50k	51.042	51.455	0.4126
16	50	Unbiased-50k	50.723	52.263	1.5399
17	60	Biased-50k	51.512	52.509	0.9968
18	60	Biased-50k	52.337	51.367	-0.9697
19	60	Biased-50k	51.316	51.843	0.5271
20	60	Biased-50k	51.362	51.337	-0.025
21	60	Biased-50k	51.271	51.825	0.5543
24	100	Unbiased-100k	51.132	52.757	1.6257
25	100	Unbiased-100k	51.194	51.064	-0.13
26	100	Unbiased-100k	51.748	52.1	0.3512
27	100	Unbiased-100k	51.498	51.505	0.006
28	100	Unbiased-100k	51.296	51.489	0.1928
29	110	Biased-100k	51.3	52.625	1.3254
30	110	Biased-100k	51.271	51.03	-0.2409
31	110	Biased-100k	51.43	51.718	0.2881
32	110	Biased-100k	51.754	50.843	-0.9108
34	110	Biased-100k	50.9	52.04	1.1395

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.145	52.266	52.41	0.13411	51.914	52.546	52.94	0.55247	-0.4962	0.27953	0.6966	0.67244
50	50.723	51.053	51.245	0.1983	51.097	51.686	52.263	0.5212	-0.0293	0.633	1.5399	0.62185
60	51.271	51.559	52.337	0.44394	51.337	51.776	52.509	0.47531	-0.9697	0.2167	0.9968	0.75578
100	51.132	51.374	51.748	0.25147	51.064	51.783	52.757	0.65774	-0.13	0.40914	1.6257	0.70416
110	50.9	51.331	51.754	0.30776	50.843	51.651	52.625	0.73196	-0.9108	0.32026	1.3254	0.93714

Device Test: 50.4 R_HS_7V_25C(HsRdson|HighSide/SW4/7/7/0.5//90.9/634//1.8///@R_HS_7V_25C)





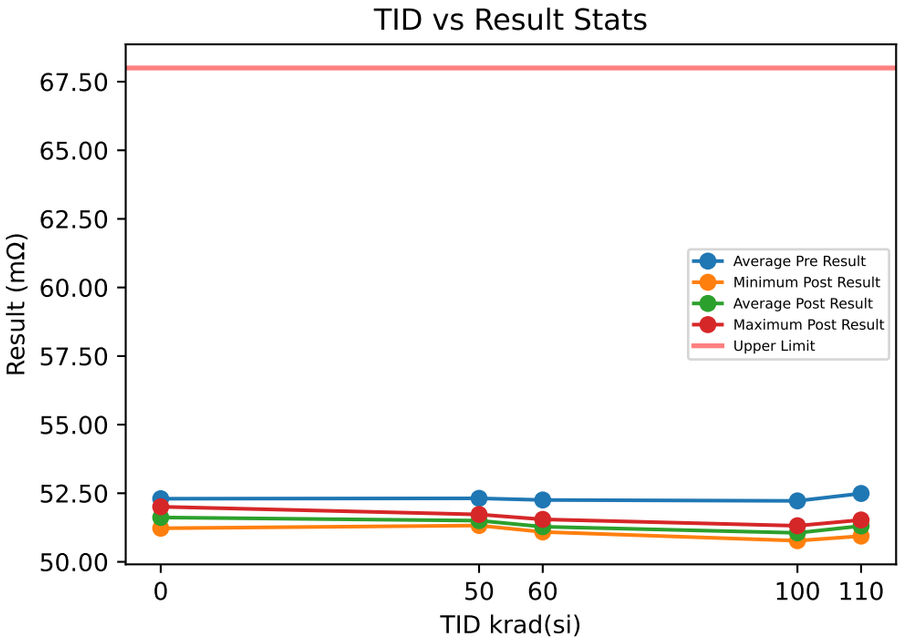
Test Results (Upper Limit = 76.0 (mΩ))

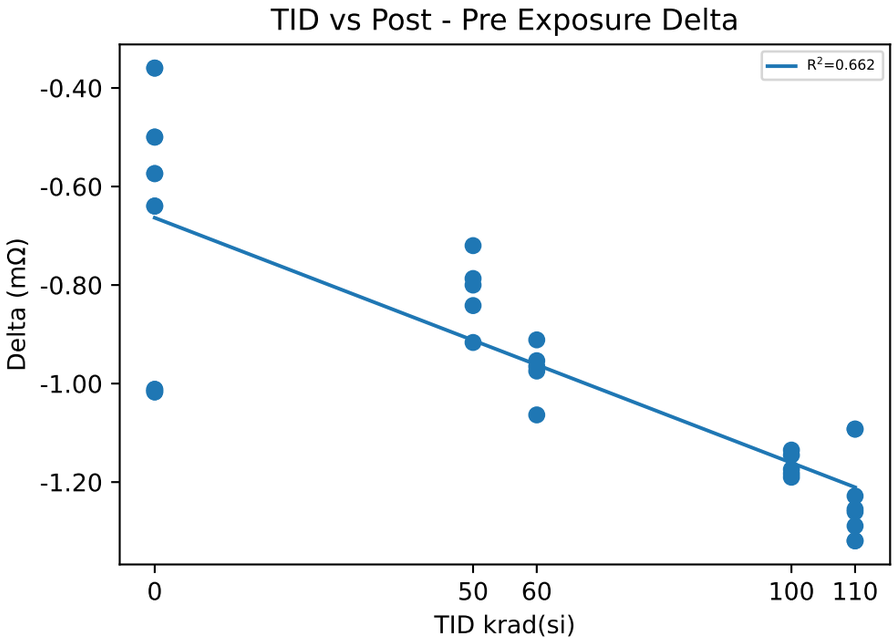
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	53.833	52.317	-1.5154
2	0	CU2	51.925	51.756	-0.1695
3	0	CU3	53.677	52.318	-1.3591
11	50	Unbiased-50k	52.628	51.348	-1.2801
12	50	Unbiased-50k	52.911	51.113	-1.7982
13	50	Unbiased-50k	52.136	50.717	-1.4193
14	50	Unbiased-50k	52.084	51.942	-0.1425
16	50	Unbiased-50k	52.473	51.341	-1.1318
17	60	Biased-50k	53.272	51.643	-1.6293
18	60	Biased-50k	53.017	51.014	-2.0021
19	60	Biased-50k	52.303	51.626	-0.6773
20	60	Biased-50k	51.671	50.242	-1.4285
21	60	Biased-50k	52.845	51.73	-1.1144
24	100	Unbiased-100k	52.548	50.736	-1.812
25	100	Unbiased-100k	51.592	51.106	-0.4864
26	100	Unbiased-100k	51.529	50.91	-0.6188
27	100	Unbiased-100k	51.641	50.705	-0.936
28	100	Unbiased-100k	51.818	51.07	-0.7477
29	110	Biased-100k	52.488	50.981	-1.5076
30	110	Biased-100k	52.777	51.005	-1.7721
31	110	Biased-100k	52.151	50.762	-1.3899
32	110	Biased-100k	52.288	52.58	0.292
34	110	Biased-100k	52.55	50.593	-1.9575

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.925	53.145	53.833	1.0593	51.756	52.13	52.318	0.32447	-1.5154	-1.0147	-0.1695	0.7361
50	52.084	52.446	52.911	0.34542	50.717	51.292	51.942	0.44464	-1.7982	-1.1544	-0.1425	0.61743
60	51.671	52.621	53.272	0.63934	50.242	51.251	51.73	0.63202	-2.0021	-1.3703	-0.6773	0.50383
100	51.529	51.826	52.548	0.418	50.705	50.906	51.106	0.18461	-1.812	-0.92018	-0.4864	0.52544
110	52.151	52.451	52.777	0.24175	50.593	51.184	52.58	0.79843	-1.9575	-1.267	0.292	0.89936

Device Test: 51.1 R_LS_3V_25C(LsRdson|LowSide/SW1/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C)





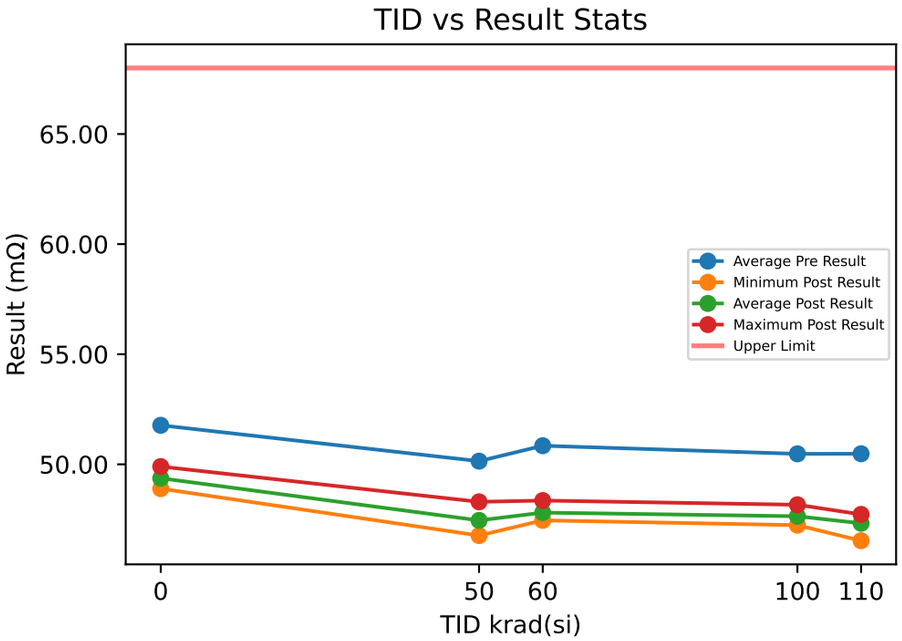
Test Results (Upper Limit = 68.0 (mΩ))

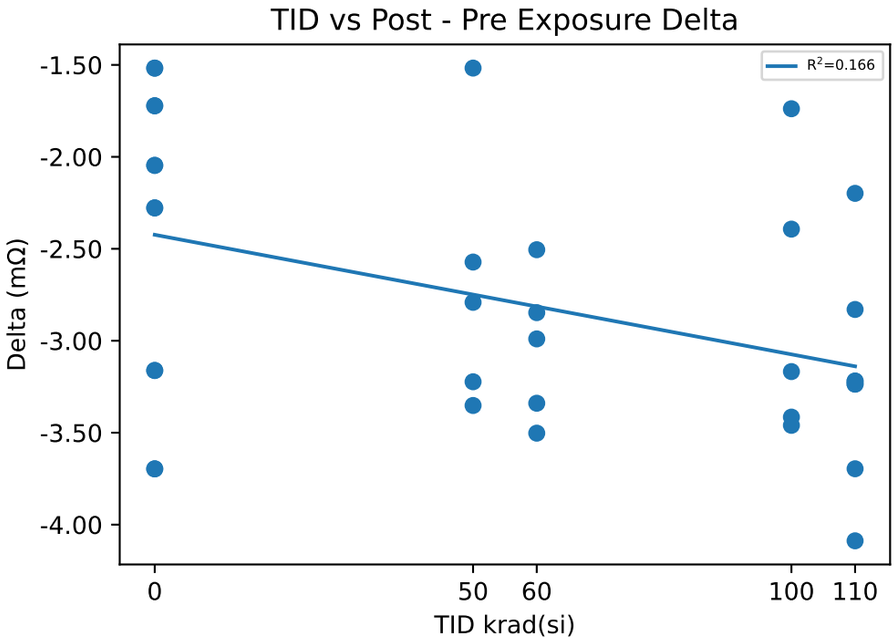
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	52.236	51.596	-0.6397
2	0	CU2	52.507	52.007	-0.4997
3	0	CU3	52.16	51.587	-0.5738
11	50	Unbiased-50k	52.589	51.672	-0.9166
12	50	Unbiased-50k	52.233	51.432	-0.8
13	50	Unbiased-50k	52.137	51.35	-0.7868
14	50	Unbiased-50k	52.165	51.324	-0.8417
16	50	Unbiased-50k	52.446	51.726	-0.72
17	60	Biased-50k	52.569	51.506	-1.0636
18	60	Biased-50k	52.041	51.13	-0.9113
19	60	Biased-50k	52.063	51.089	-0.9746
20	60	Biased-50k	52.096	51.13	-0.9652
21	60	Biased-50k	52.501	51.547	-0.9536
24	100	Unbiased-100k	52.498	51.315	-1.1829
25	100	Unbiased-100k	51.944	50.77	-1.1742
26	100	Unbiased-100k	51.961	50.826	-1.135
27	100	Unbiased-100k	52.202	51.056	-1.1452
28	100	Unbiased-100k	52.502	51.312	-1.1901
29	110	Biased-100k	52.193	50.938	-1.2549
30	110	Biased-100k	52.692	51.431	-1.2604
31	110	Biased-100k	52.642	51.414	-1.2283
32	110	Biased-100k	52.31	51.021	-1.2891
34	110	Biased-100k	52.618	51.299	-1.3192

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.16	52.301	52.507	0.18208	51.587	51.73	52.007	0.23999	-0.6397	-0.57107	-0.4997	0.07004
50	52.137	52.314	52.589	0.19557	51.324	51.501	51.726	0.18634	-0.9166	-0.81302	-0.72	0.072562
60	52.041	52.254	52.569	0.25851	51.089	51.28	51.547	0.22588	-1.0636	-0.97366	-0.9113	0.055796
100	51.944	52.221	52.502	0.274	50.77	51.056	51.315	0.25853	-1.1901	-1.1655	-1.135	0.024114
110	52.193	52.491	52.692	0.22407	50.938	51.221	51.431	0.22781	-1.3192	-1.2704	-1.2283	0.034799

Device Test: 51.2 R_LS_3V_25C(LsRdson|LowSide/SW2/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C)





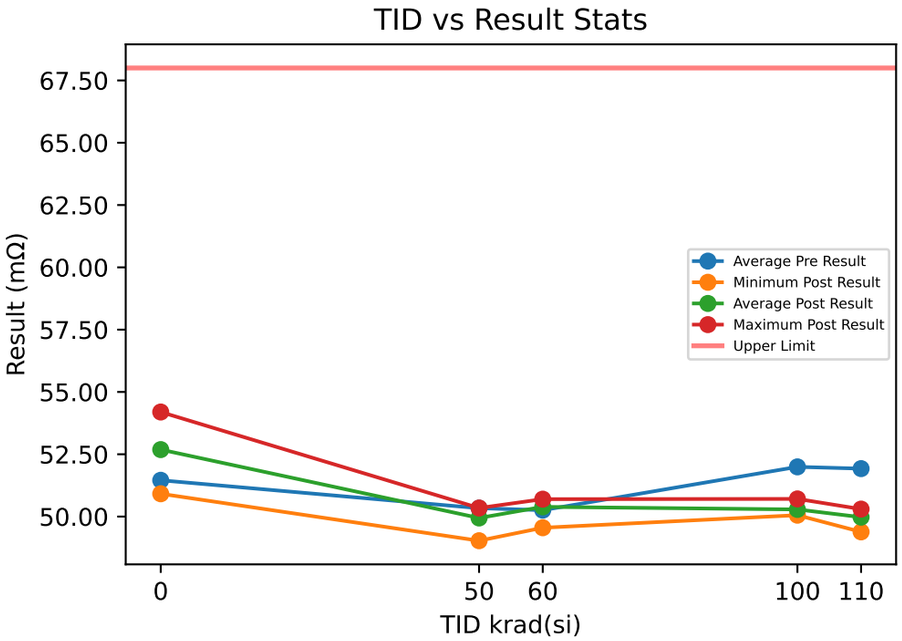
Test Results (Upper Limit = 68.0 (mΩ))

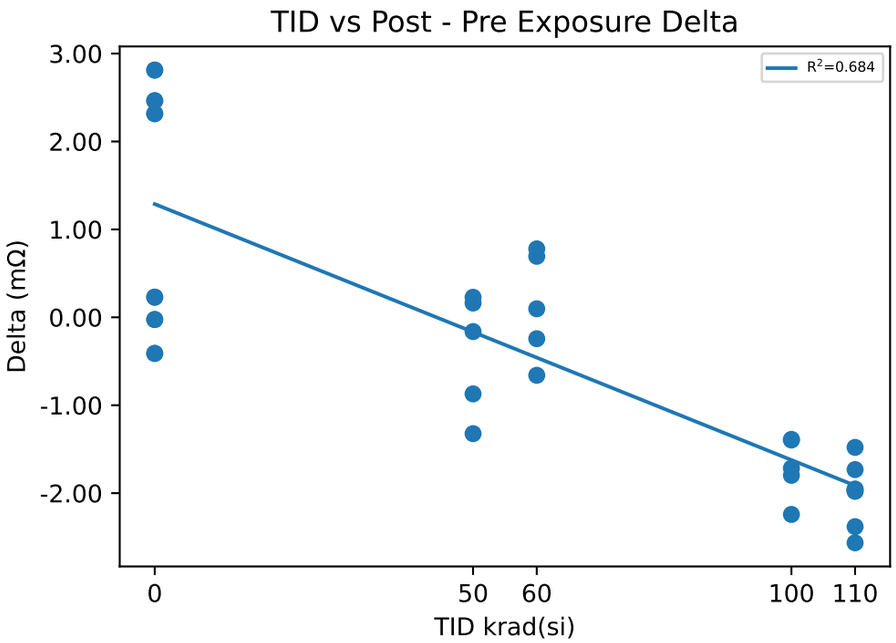
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	53.06	49.898	-3.1617
2	0	CU2	50.941	48.894	-2.0464
3	0	CU3	51.315	49.797	-1.5175
11	50	Unbiased-50k	50.112	47.539	-2.5721
12	50	Unbiased-50k	50.471	47.68	-2.7911
13	50	Unbiased-50k	50.204	46.981	-3.223
14	50	Unbiased-50k	50.117	46.765	-3.352
16	50	Unbiased-50k	49.814	48.296	-1.5173
17	60	Biased-50k	50.51	47.52	-2.9899
18	60	Biased-50k	51.183	47.844	-3.3398
19	60	Biased-50k	50.958	47.455	-3.5025
20	60	Biased-50k	50.367	47.862	-2.505
21	60	Biased-50k	51.201	48.354	-2.8472
24	100	Unbiased-100k	50.456	48.063	-2.393
25	100	Unbiased-100k	50.878	47.418	-3.4599
26	100	Unbiased-100k	49.902	48.164	-1.7384
27	100	Unbiased-100k	50.739	47.324	-3.4152
28	100	Unbiased-100k	50.404	47.237	-3.1677
29	110	Biased-100k	49.924	47.726	-2.1985
30	110	Biased-100k	50.975	47.279	-3.6961
31	110	Biased-100k	50.241	47.411	-2.8299
32	110	Biased-100k	50.618	46.53	-4.0879
34	110	Biased-100k	50.636	47.417	-3.2193

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.941	51.772	53.06	1.1311	48.894	49.53	49.898	0.5527	-3.1617	-2.2419	-1.5175	0.83935
50	49.814	50.143	50.471	0.23517	46.765	47.452	48.296	0.60543	-3.352	-2.6911	-1.5173	0.7283
60	50.367	50.844	51.201	0.38543	47.455	47.807	48.354	0.3569	-3.5025	-3.0369	-2.505	0.39675
100	49.902	50.476	50.878	0.37601	47.237	47.641	48.164	0.43735	-3.4599	-2.8348	-1.7384	0.74762
110	49.924	50.479	50.975	0.40456	46.53	47.273	47.726	0.44628	-4.0879	-3.2063	-2.1985	0.73733

Device Test: 51.3 R_LS_3V_25C(LsRdson|LowSide/SW3/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C)





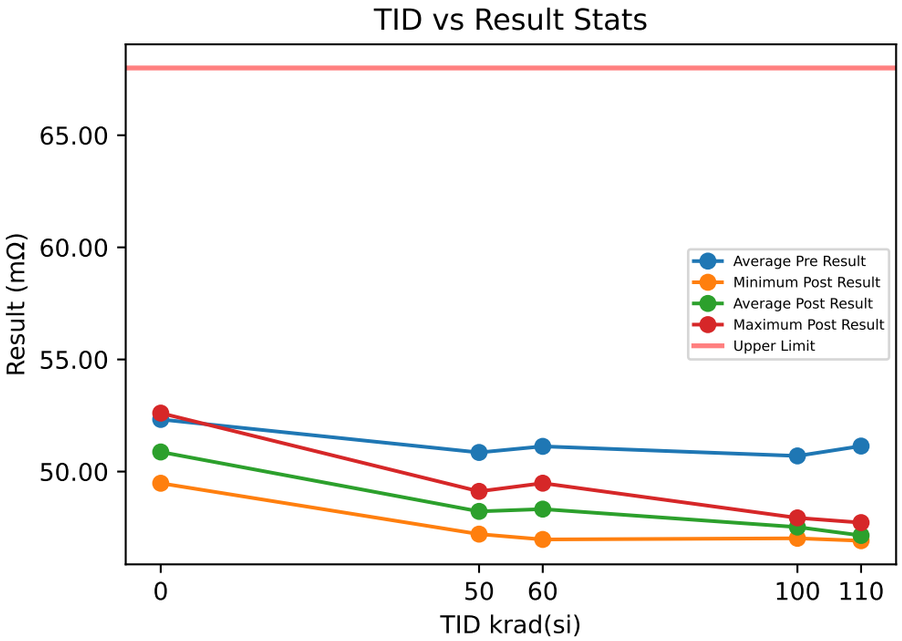
Test Results (Upper Limit = 68.0 (mΩ))

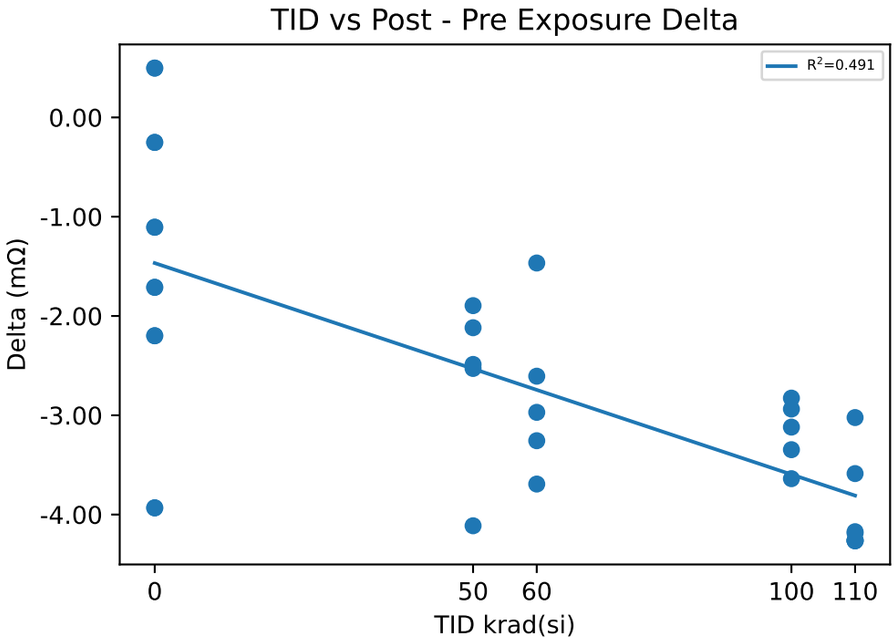
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	51.879	52.108	0.2293
2	0	CU2	51.163	51.138	-0.0252
3	0	CU3	51.326	54.138	2.8123
11	50	Unbiased-50k	50.053	50.215	0.1623
12	50	Unbiased-50k	50.115	50.343	0.2279
13	50	Unbiased-50k	50.924	50.053	-0.8711
14	50	Unbiased-50k	50.354	49.031	-1.3234
16	50	Unbiased-50k	50.236	50.073	-0.1624
17	60	Biased-50k	49.92	50.698	0.7784
18	60	Biased-50k	50.211	49.551	-0.6595
19	60	Biased-50k	50.524	50.621	0.0968
20	60	Biased-50k	49.981	50.675	0.6938
21	60	Biased-50k	50.645	50.402	-0.2435
24	100	Unbiased-100k	52.425	50.708	-1.7164
25	100	Unbiased-100k	52.298	50.055	-2.2422
26	100	Unbiased-100k	51.654	50.266	-1.3886
27	100	Unbiased-100k	51.728	50.333	-1.3959
28	100	Unbiased-100k	51.866	50.069	-1.7972
29	110	Biased-100k	51.822	50.09	-1.7321
30	110	Biased-100k	51.093	49.614	-1.4797
31	110	Biased-100k	52.865	50.3	-2.5651
32	110	Biased-100k	51.767	49.386	-2.3813
34	110	Biased-100k	52.071	50.116	-1.9552

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.163	51.456	51.879	0.37503	51.138	52.461	54.138	1.5308	-0.0252	1.0055	2.8123	1.5699
50	50.053	50.336	50.924	0.34817	49.031	49.943	50.343	0.52327	-1.3234	-0.39334	0.2279	0.67847
60	49.92	50.256	50.645	0.32177	49.551	50.389	50.698	0.48306	-0.6595	0.1332	0.7784	0.61281
100	51.654	51.994	52.425	0.34649	50.055	50.286	50.708	0.26522	-2.2422	-1.7081	-1.3886	0.35101
110	51.093	51.924	52.865	0.63857	49.386	49.901	50.3	0.38356	-2.5651	-2.0227	-1.4797	0.44907

Device Test: 51.4 R_LS_3V_25C(LsRdson|LowSide/SW4/3/3/0.5//90.9/634//1.8///@R_LS_3V_25C)





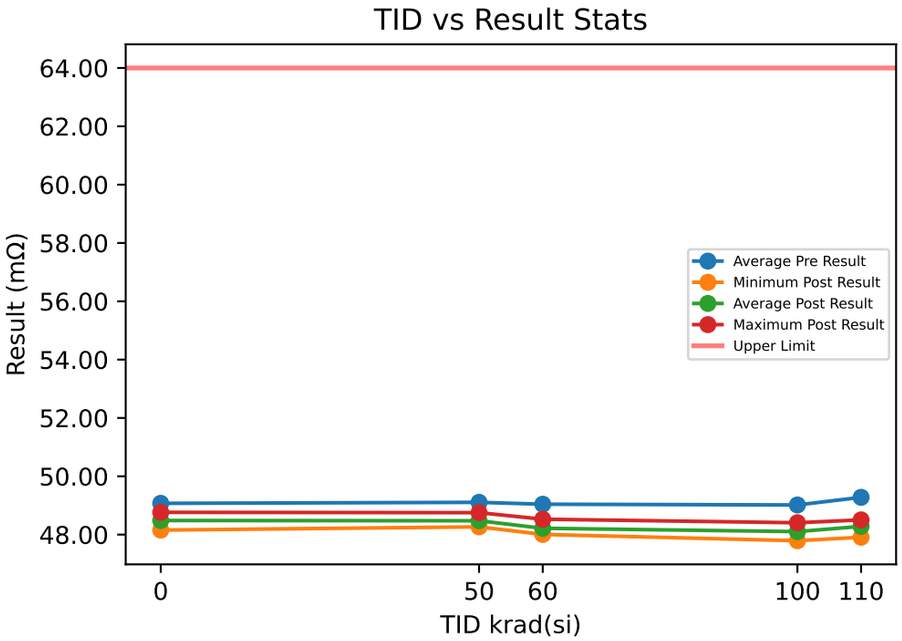
Test Results (Upper Limit = 68.0 (mΩ))

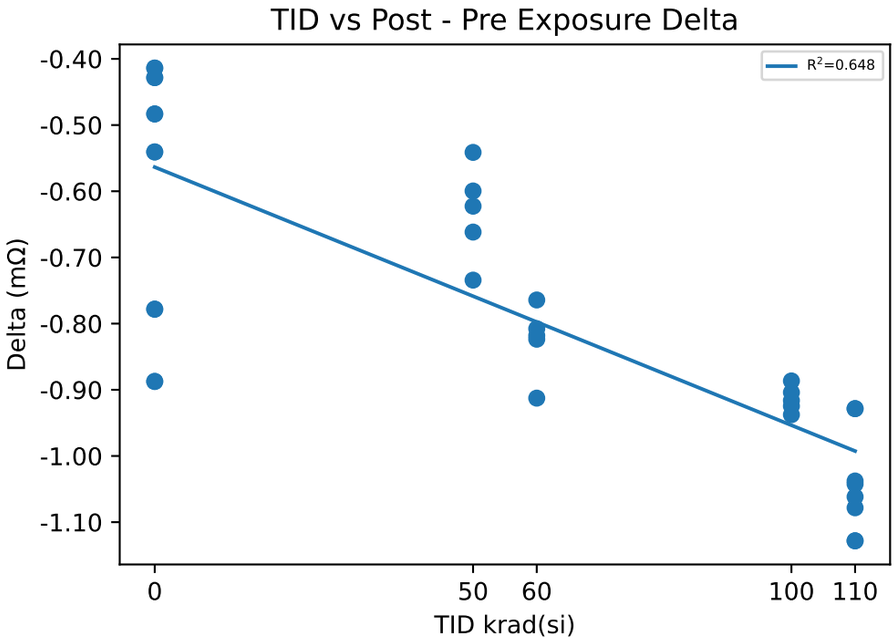
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	54.806	52.607	-2.1991
2	0	CU2	51.19	50.084	-1.1062
3	0	CU3	50.977	50.725	-0.2518
11	50	Unbiased-50k	51.013	49.117	-1.8957
12	50	Unbiased-50k	50.334	48.216	-2.1182
13	50	Unbiased-50k	51.323	47.21	-4.1129
14	50	Unbiased-50k	50.521	48.033	-2.4879
16	50	Unbiased-50k	51.071	48.542	-2.5285
17	60	Biased-50k	51.289	48.318	-2.9705
18	60	Biased-50k	51.967	48.274	-3.6927
19	60	Biased-50k	50.948	49.482	-1.4664
20	60	Biased-50k	50.228	46.972	-3.2562
21	60	Biased-50k	51.187	48.581	-2.6064
24	100	Unbiased-100k	50.872	47.935	-2.9371
25	100	Unbiased-100k	51.095	47.456	-3.6386
26	100	Unbiased-100k	49.85	47.023	-2.8271
27	100	Unbiased-100k	50.712	47.593	-3.1192
28	100	Unbiased-100k	50.962	47.615	-3.3466
29	110	Biased-100k	51.311	47.724	-3.5873
30	110	Biased-100k	50.503	47.48	-3.0231
31	110	Biased-100k	51.332	47.159	-4.1726
32	110	Biased-100k	51.361	47.173	-4.1876
34	110	Biased-100k	51.18	46.92	-4.2601

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.977	52.325	54.806	2.1518	50.084	51.139	52.607	1.3114	-2.1991	-1.1857	-0.2518	0.97608
50	50.334	50.852	51.323	0.41027	47.21	48.224	49.117	0.7008	-4.1129	-2.6286	-1.8957	0.87043
60	50.228	51.124	51.967	0.62746	46.972	48.325	49.482	0.89937	-3.6927	-2.7984	-1.4664	0.84411
100	49.85	50.698	51.095	0.49393	47.023	47.524	47.935	0.33056	-3.6386	-3.1737	-2.8271	0.326
110	50.503	51.137	51.361	0.36124	46.92	47.291	47.724	0.31288	-4.2601	-3.8461	-3.0231	0.5336

Device Test: 52.1 R_LS_5V_25C(LsRdson|LowSide/SW1/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C)





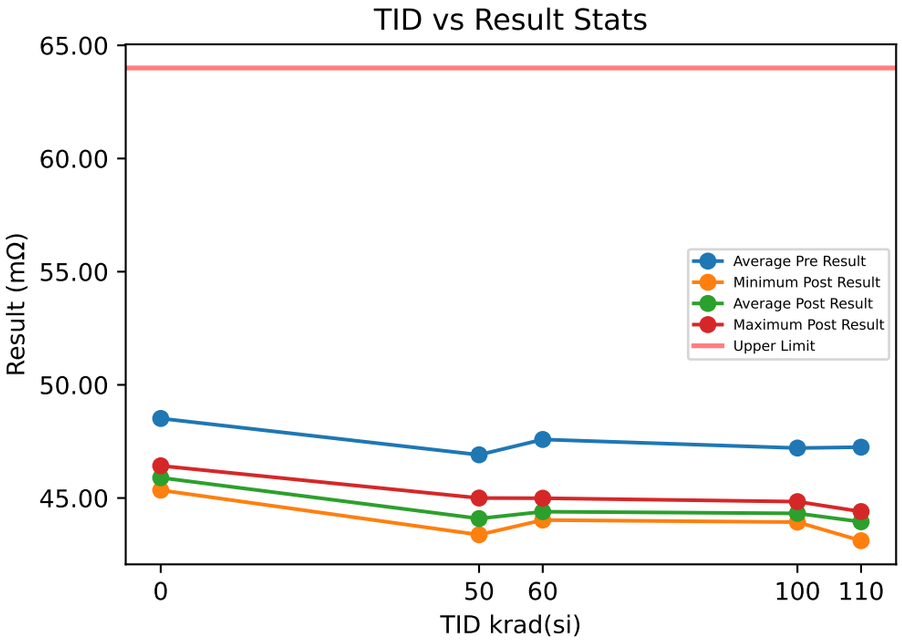
Test Results (Upper Limit = 64.0 (mΩ))

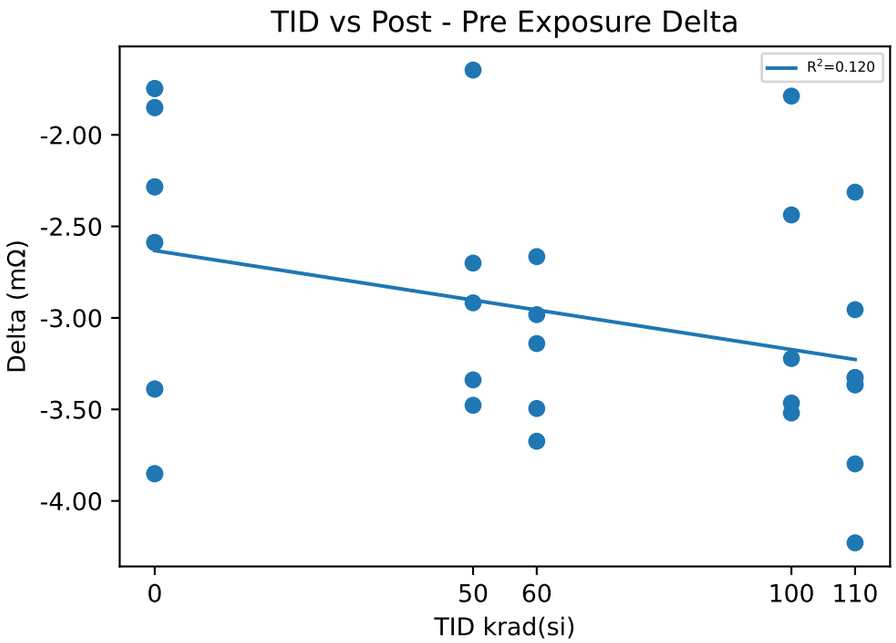
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	49.042	48.501	-0.5406
2	0	CU2	49.177	48.763	-0.4139
3	0	CU3	48.997	48.514	-0.4832
11	50	Unbiased-50k	49.395	48.661	-0.7343
12	50	Unbiased-50k	49.035	48.412	-0.6226
13	50	Unbiased-50k	48.881	48.281	-0.5996
14	50	Unbiased-50k	48.928	48.266	-0.6617
16	50	Unbiased-50k	49.294	48.752	-0.5413
17	60	Biased-50k	49.4	48.487	-0.9126
18	60	Biased-50k	48.794	48.03	-0.7643
19	60	Biased-50k	48.83	48.006	-0.8236
20	60	Biased-50k	48.85	48.032	-0.8181
21	60	Biased-50k	49.335	48.528	-0.8077
24	100	Unbiased-100k	49.284	48.359	-0.9246
25	100	Unbiased-100k	48.707	47.79	-0.9162
26	100	Unbiased-100k	48.753	47.866	-0.8866
27	100	Unbiased-100k	48.995	48.091	-0.904
28	100	Unbiased-100k	49.344	48.407	-0.9376
29	110	Biased-100k	48.971	47.91	-1.0617
30	110	Biased-100k	49.547	48.504	-1.0424
31	110	Biased-100k	49.422	48.384	-1.0378
32	110	Biased-100k	49.051	47.973	-1.0783
34	110	Biased-100k	49.399	48.271	-1.1282

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.997	49.072	49.177	0.093899	48.501	48.593	48.763	0.14787	-0.5406	-0.47923	-0.4139	0.063443
50	48.881	49.106	49.395	0.22734	48.266	48.475	48.752	0.22189	-0.7343	-0.6319	-0.5413	0.071958
60	48.794	49.042	49.4	0.29882	48.006	48.217	48.528	0.26598	-0.9126	-0.82526	-0.7643	0.054099
100	48.707	49.017	49.344	0.2936	47.79	48.103	48.407	0.27915	-0.9376	-0.9138	-0.8866	0.019524
110	48.971	49.278	49.547	0.25145	47.91	48.208	48.504	0.25831	-1.1282	-1.0697	-1.0378	0.03648

Device Test: 52.2 R_LS_5V_25C(LsRdson|LowSide/SW2/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C)





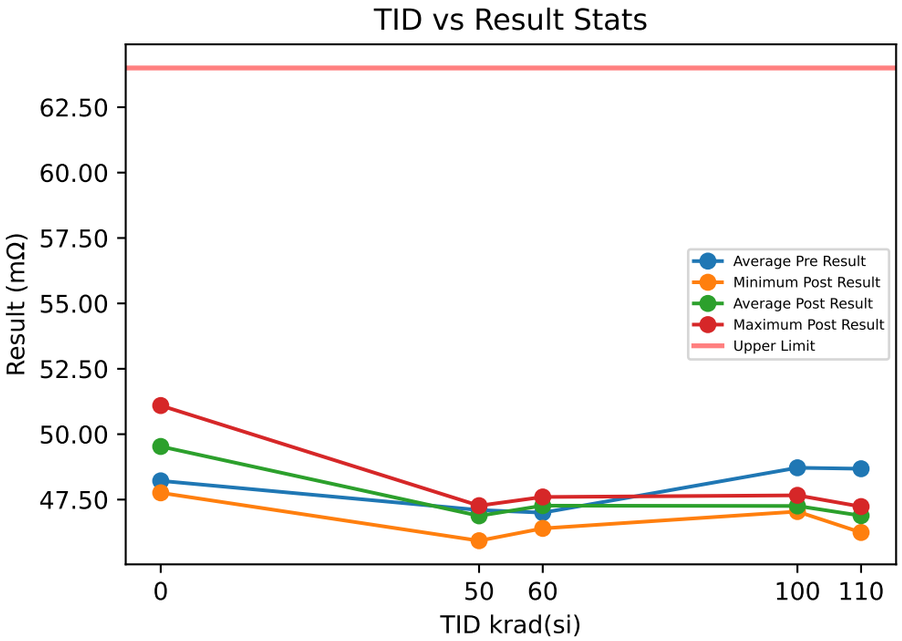
Test Results (Upper Limit = 64.0 (mΩ))

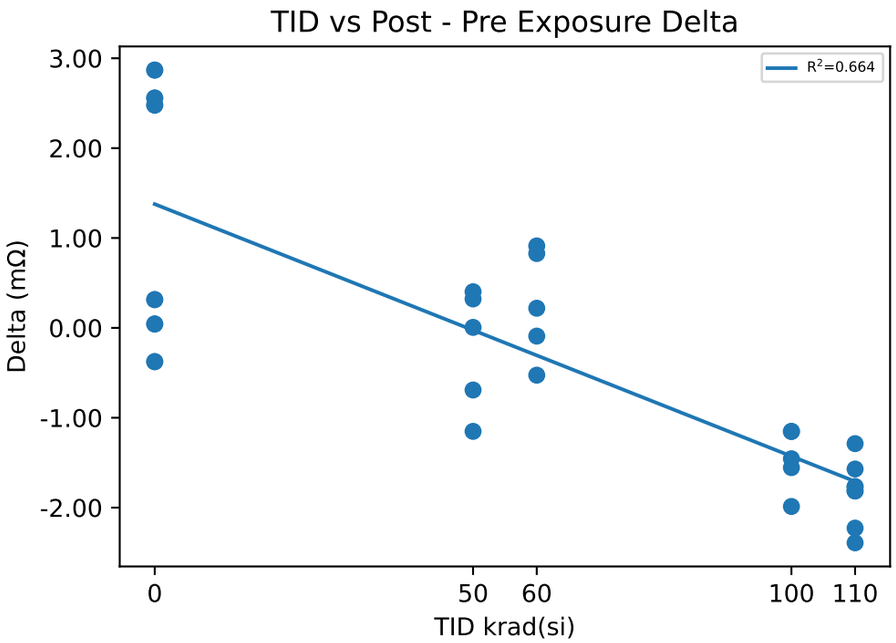
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	49.812	46.423	-3.3886
2	0	CU2	47.63	45.346	-2.2842
3	0	CU3	48.103	46.356	-1.747
11	50	Unbiased-50k	46.893	44.193	-2.7006
12	50	Unbiased-50k	47.226	44.308	-2.9179
13	50	Unbiased-50k	46.924	43.585	-3.3388
14	50	Unbiased-50k	46.854	43.377	-3.4775
16	50	Unbiased-50k	46.645	44.999	-1.6461
17	60	Biased-50k	47.266	44.126	-3.1402
18	60	Biased-50k	47.901	44.406	-3.495
19	60	Biased-50k	47.7	44.026	-3.6739
20	60	Biased-50k	47.091	44.426	-2.6653
21	60	Biased-50k	47.974	44.991	-2.9823
24	100	Unbiased-100k	47.188	44.751	-2.4375
25	100	Unbiased-100k	47.612	44.092	-3.5196
26	100	Unbiased-100k	46.628	44.84	-1.7883
27	100	Unbiased-100k	47.453	43.988	-3.4653
28	100	Unbiased-100k	47.157	43.935	-3.2221
29	110	Biased-100k	46.714	44.401	-2.313
30	110	Biased-100k	47.826	44.029	-3.7976
31	110	Biased-100k	47.003	44.048	-2.9552
32	110	Biased-100k	47.342	43.113	-4.2289
34	110	Biased-100k	47.348	44.022	-3.3262

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.63	48.515	49.812	1.1477	45.346	46.042	46.423	0.60374	-3.3886	-2.4733	-1.747	0.83697
50	46.645	46.908	47.226	0.20822	43.377	44.092	44.999	0.64191	-3.4775	-2.8162	-1.6461	0.72513
60	47.091	47.586	47.974	0.39041	44.026	44.395	44.991	0.37582	-3.6739	-3.1913	-2.6653	0.40252
100	46.628	47.208	47.612	0.37495	43.935	44.321	44.84	0.43767	-3.5196	-2.8866	-1.7883	0.75102
110	46.714	47.247	47.826	0.41784	43.113	43.923	44.401	0.47982	-4.2289	-3.3242	-2.313	0.74184

Device Test: 52.3 R_LS_5V_25C(LsRdson|LowSide/SW3/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C)





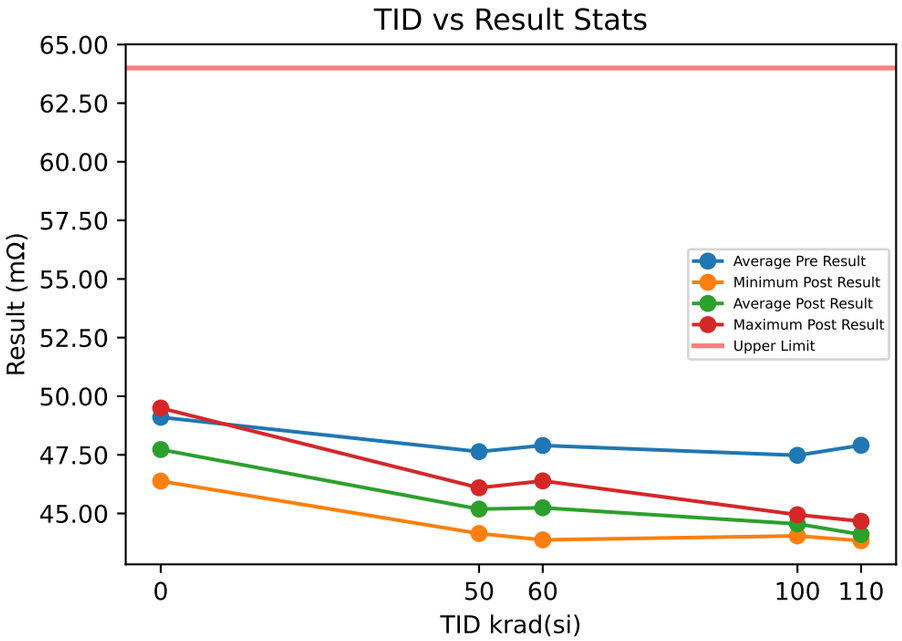
Test Results (Upper Limit = 64.0 (mΩ))

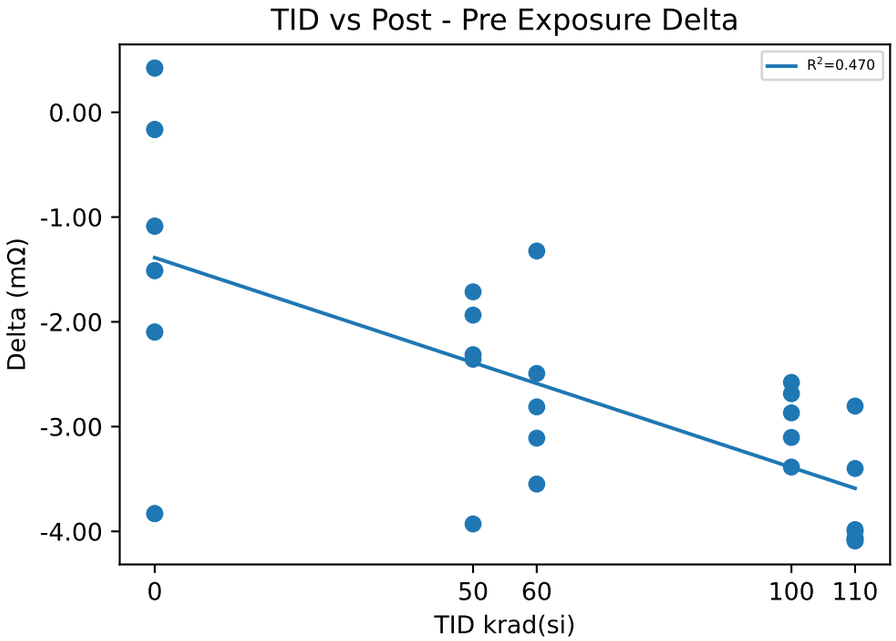
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	48.617	48.931	0.3144
2	0	CU2	47.897	47.94	0.0432
3	0	CU3	48.135	51.003	2.8685
11	50	Unbiased-50k	46.844	47.166	0.322
12	50	Unbiased-50k	46.865	47.267	0.4022
13	50	Unbiased-50k	47.654	46.963	-0.6913
14	50	Unbiased-50k	47.079	45.928	-1.1514
16	50	Unbiased-50k	47.064	47.07	0.0056
17	60	Biased-50k	46.688	47.599	0.9119
18	60	Biased-50k	46.925	46.398	-0.5261
19	60	Biased-50k	47.267	47.486	0.2187
20	60	Biased-50k	46.702	47.529	0.8273
21	60	Biased-50k	47.42	47.329	-0.0916
24	100	Unbiased-100k	49.119	47.662	-1.4563
25	100	Unbiased-100k	49.03	47.043	-1.9872
26	100	Unbiased-100k	48.37	47.218	-1.1514
27	100	Unbiased-100k	48.455	47.302	-1.1527
28	100	Unbiased-100k	48.608	47.053	-1.5548
29	110	Biased-100k	48.588	47.017	-1.5705
30	110	Biased-100k	47.936	46.648	-1.2881
31	110	Biased-100k	49.624	47.232	-2.3916
32	110	Biased-100k	48.471	46.243	-2.2281
34	110	Biased-100k	48.777	47.01	-1.7668

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.897	48.216	48.617	0.36678	47.94	49.292	51.003	1.5631	0.0432	1.0754	2.8685	1.5588
50	46.844	47.101	47.654	0.32762	45.928	46.879	47.267	0.54351	-1.1514	-0.22258	0.4022	0.67479
60	46.688	47	47.42	0.33169	46.398	47.268	47.599	0.49634	-0.5261	0.26804	0.9119	0.61028
100	48.37	48.716	49.119	0.33927	47.043	47.256	47.662	0.25262	-1.9872	-1.4605	-1.1514	0.34518
110	47.936	48.679	49.624	0.61356	46.243	46.83	47.232	0.3896	-2.3916	-1.849	-1.2881	0.45745

Device Test: 52.4 R_LS_5V_25C(LsRdson|LowSide/SW4/5/5/0.5//90.9/634//1.8///@R_LS_5V_25C)





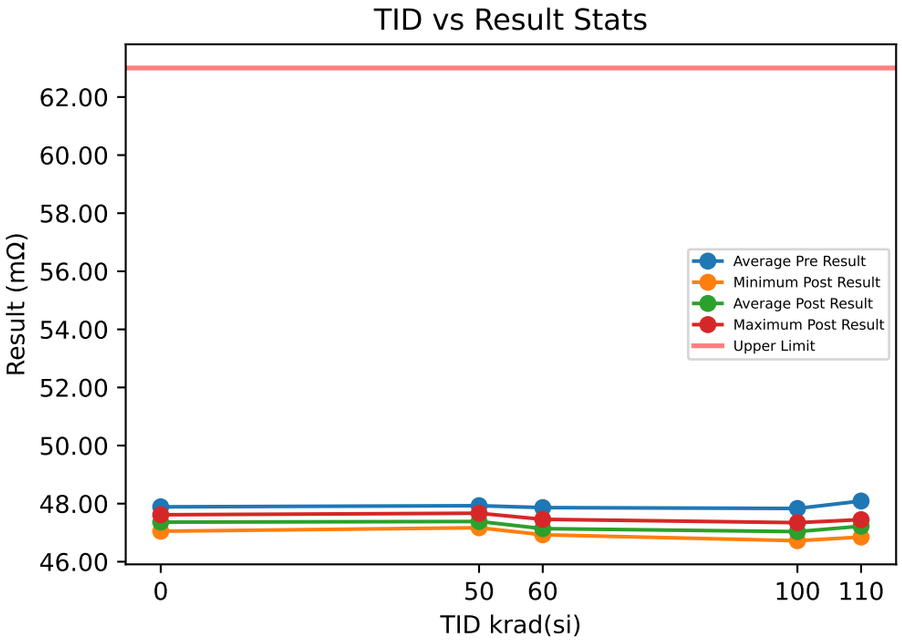
Test Results (Upper Limit = 64.0 (mΩ))

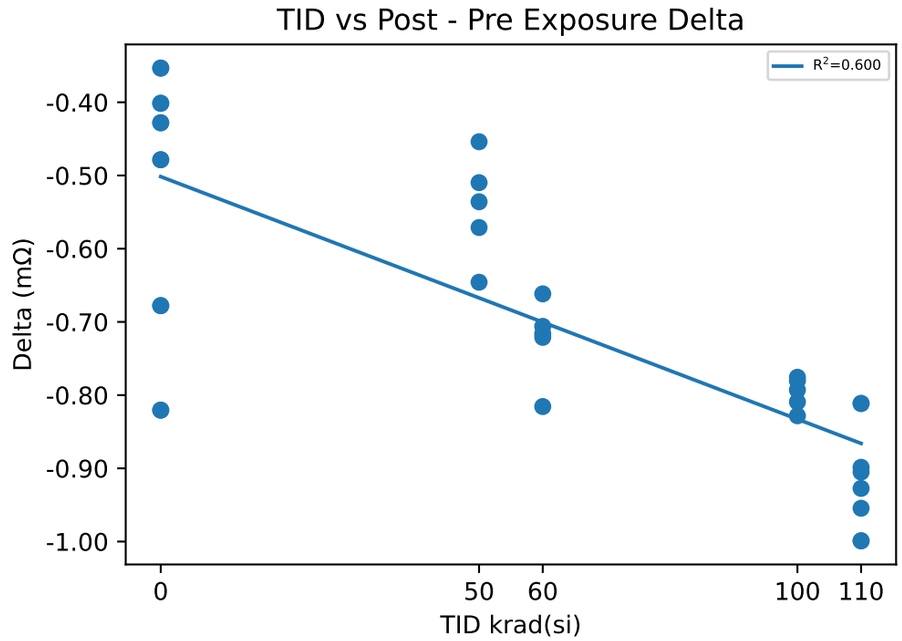
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	51.593	49.495	-2.0975
2	0	CU2	47.89	46.803	-1.0871
3	0	CU3	47.828	47.663	-0.1645
11	50	Unbiased-50k	47.809	46.095	-1.7137
12	50	Unbiased-50k	47.116	45.181	-1.9357
13	50	Unbiased-50k	48.074	44.145	-3.9291
14	50	Unbiased-50k	47.267	44.954	-2.3134
16	50	Unbiased-50k	47.913	45.556	-2.3571
17	60	Biased-50k	48.088	45.277	-2.8117
18	60	Biased-50k	48.712	45.163	-3.5484
19	60	Biased-50k	47.713	46.389	-1.324
20	60	Biased-50k	46.983	43.873	-3.1101
21	60	Biased-50k	48.001	45.508	-2.4927
24	100	Unbiased-100k	47.632	44.946	-2.6858
25	100	Unbiased-100k	47.847	44.461	-3.3861
26	100	Unbiased-100k	46.621	44.043	-2.5781
27	100	Unbiased-100k	47.493	44.624	-2.869
28	100	Unbiased-100k	47.804	44.7	-3.1032
29	110	Biased-100k	48.068	44.668	-3.3998
30	110	Biased-100k	47.343	44.538	-2.8041
31	110	Biased-100k	48.11	44.127	-3.9831
32	110	Biased-100k	48.09	44.092	-3.9976
34	110	Biased-100k	47.927	43.862	-4.065

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.828	49.104	51.593	2.1561	46.803	47.987	49.495	1.3751	-2.0975	-1.1164	-0.1645	0.96683
50	47.116	47.636	48.074	0.41955	44.145	45.186	46.095	0.72466	-3.9291	-2.4498	-1.7137	0.86915
60	46.983	47.899	48.712	0.62852	43.873	45.242	46.389	0.90376	-3.5484	-2.6574	-1.324	0.84079
100	46.621	47.479	47.847	0.50018	44.043	44.555	44.946	0.33557	-3.3861	-2.9244	-2.5781	0.32598
110	47.343	47.907	48.11	0.32387	43.862	44.258	44.668	0.33483	-4.065	-3.6499	-2.8041	0.54363

Device Test: 53.1 R_LS_7V_25C(LsRdson|LowSide/SW1/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C)





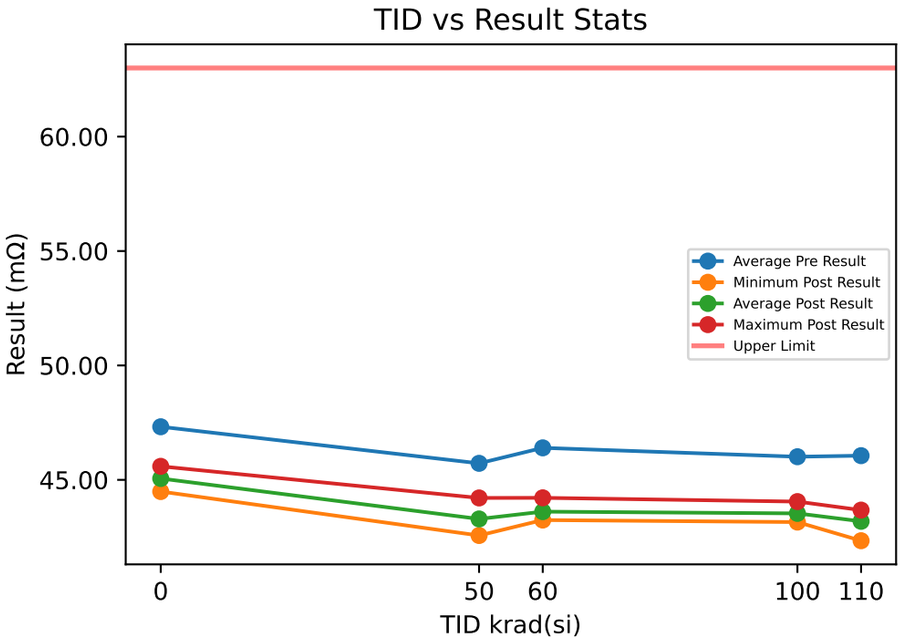
Test Results (Upper Limit = 63.0 (mΩ))

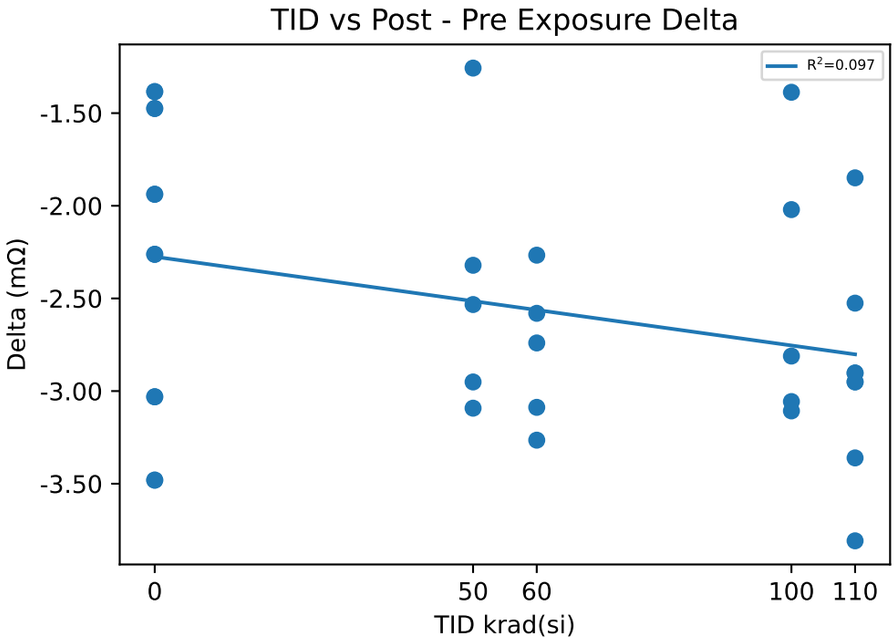
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	47.87	47.392	-0.4785
2	0	CU2	47.969	47.616	-0.3533
3	0	CU3	47.829	47.401	-0.428
11	50	Unbiased-50k	48.222	47.576	-0.6458
12	50	Unbiased-50k	47.863	47.327	-0.5359
13	50	Unbiased-50k	47.694	47.184	-0.5098
14	50	Unbiased-50k	47.741	47.17	-0.5711
16	50	Unbiased-50k	48.123	47.669	-0.4539
17	60	Biased-50k	48.224	47.408	-0.8156
18	60	Biased-50k	47.613	46.951	-0.6617
19	60	Biased-50k	47.649	46.928	-0.7211
20	60	Biased-50k	47.666	46.95	-0.7159
21	60	Biased-50k	48.166	47.459	-0.7061
24	100	Unbiased-100k	48.098	47.288	-0.8092
25	100	Unbiased-100k	47.516	46.723	-0.7929
26	100	Unbiased-100k	47.573	46.797	-0.7756
27	100	Unbiased-100k	47.81	47.029	-0.7804
28	100	Unbiased-100k	48.173	47.345	-0.8282
29	110	Biased-100k	47.776	46.849	-0.9274
30	110	Biased-100k	48.346	47.448	-0.8986
31	110	Biased-100k	48.241	47.336	-0.9051
32	110	Biased-100k	47.868	46.913	-0.9545
34	110	Biased-100k	48.215	47.216	-0.999

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.829	47.889	47.969	0.072364	47.392	47.469	47.616	0.12713	-0.4785	-0.41993	-0.3533	0.062989
50	47.694	47.929	48.222	0.23377	47.17	47.385	47.669	0.22773	-0.6458	-0.5433	-0.4539	0.071499
60	47.613	47.863	48.224	0.30367	46.928	47.139	47.459	0.26958	-0.8156	-0.72408	-0.6617	0.056272
100	47.516	47.834	48.173	0.29773	46.723	47.037	47.345	0.28029	-0.8282	-0.79726	-0.7756	0.021635
110	47.776	48.089	48.346	0.251	46.849	47.152	47.448	0.26186	-0.999	-0.93692	-0.8986	0.041032

Device Test: 53.2 R_LS_7V_25C(LsRdson|LowSide/SW2/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C)





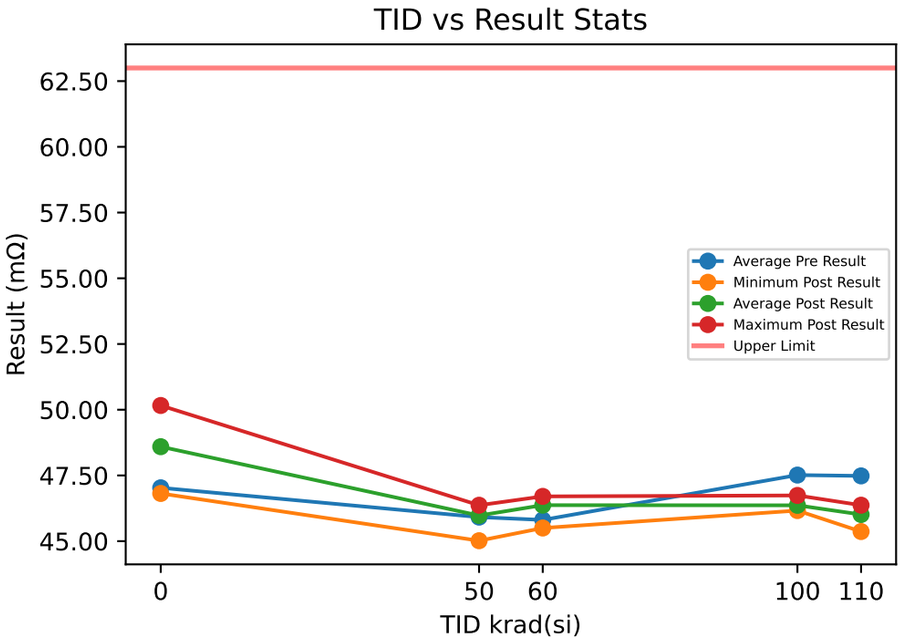
Test Results (Upper Limit = 63.0 (mΩ))

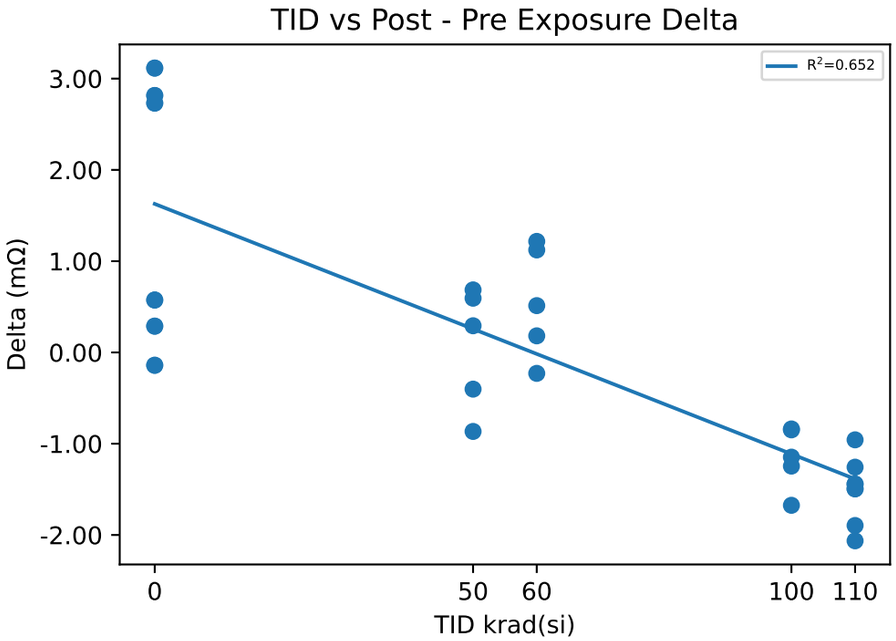
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	48.621	45.591	-3.0308
2	0	CU2	46.427	44.489	-1.9379
3	0	CU3	46.912	45.528	-1.384
11	50	Unbiased-50k	45.715	43.394	-2.3211
12	50	Unbiased-50k	46.04	43.507	-2.533
13	50	Unbiased-50k	45.729	42.778	-2.9508
14	50	Unbiased-50k	45.661	42.569	-3.0923
16	50	Unbiased-50k	45.466	44.209	-1.2569
17	60	Biased-50k	46.077	43.336	-2.7403
18	60	Biased-50k	46.706	43.619	-3.0878
19	60	Biased-50k	46.508	43.244	-3.2649
20	60	Biased-50k	45.907	43.64	-2.2666
21	60	Biased-50k	46.795	44.214	-2.5804
24	100	Unbiased-100k	45.975	43.954	-2.0207
25	100	Unbiased-100k	46.417	43.31	-3.107
26	100	Unbiased-100k	45.437	44.05	-1.3874
27	100	Unbiased-100k	46.259	43.202	-3.0566
28	100	Unbiased-100k	45.966	43.155	-2.811
29	110	Biased-100k	45.527	43.678	-1.8493
30	110	Biased-100k	46.644	43.283	-3.3607
31	110	Biased-100k	45.81	43.285	-2.5255
32	110	Biased-100k	46.148	42.34	-3.8081
34	110	Biased-100k	46.157	43.255	-2.9026

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.427	47.32	48.621	1.1527	44.489	45.203	45.591	0.61875	-3.0308	-2.1176	-1.384	0.83797
50	45.466	45.722	46.04	0.20632	42.569	43.291	44.209	0.64911	-3.0923	-2.4308	-1.2569	0.72603
60	45.907	46.399	46.795	0.39029	43.244	43.611	44.214	0.37931	-3.2649	-2.788	-2.2666	0.39829
100	45.437	46.011	46.417	0.37372	43.155	43.534	44.05	0.43216	-3.107	-2.4765	-1.3874	0.7483
110	45.527	46.057	46.644	0.41954	42.34	43.168	43.678	0.49494	-3.8081	-2.8892	-1.8493	0.75507

Device Test: 53.3 R_LS_7V_25C(LsRdson|LowSide/SW3/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C)





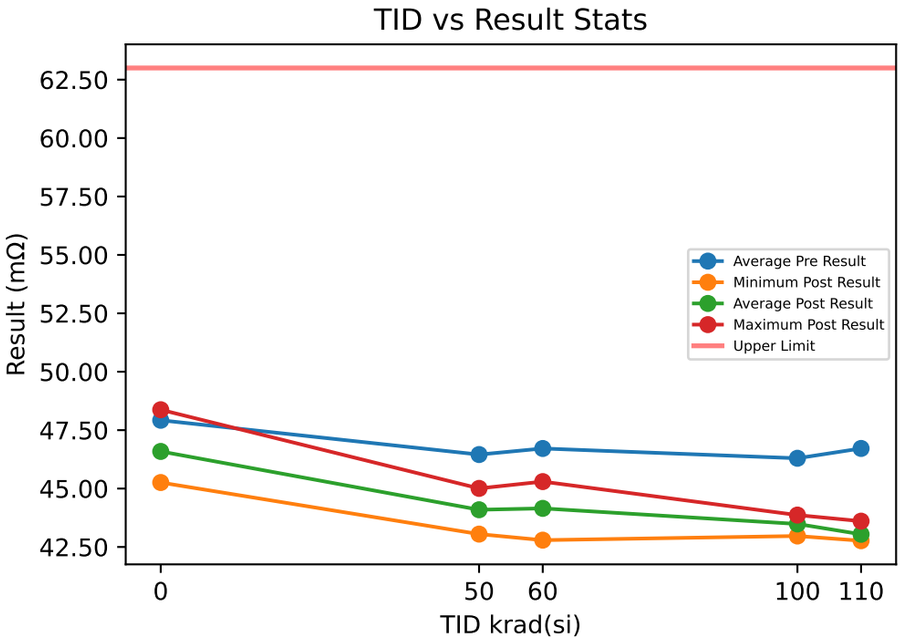
Test Results (Upper Limit = 63.0 (mΩ))

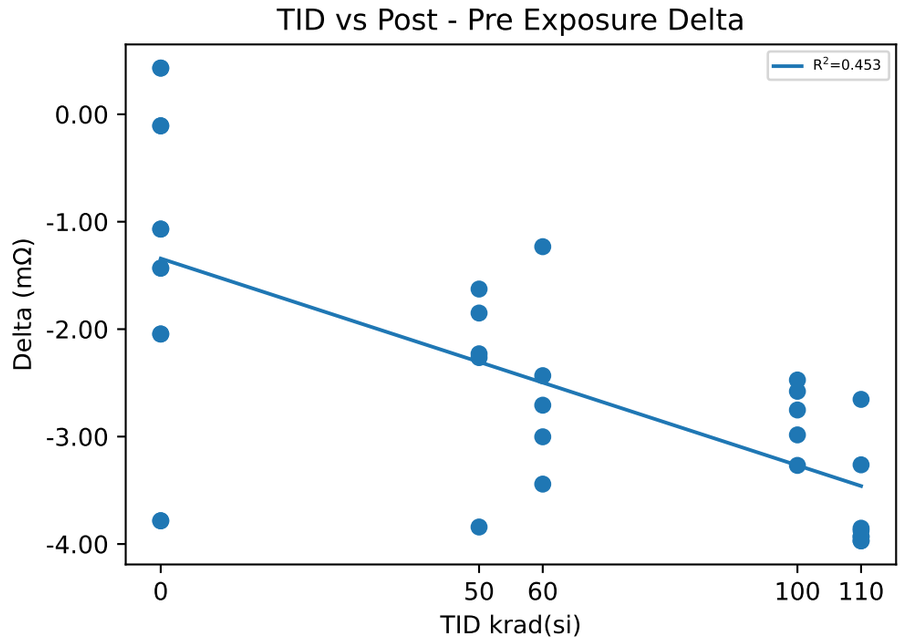
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	47.429	48.004	0.5743
2	0	CU2	46.705	46.993	0.2881
3	0	CU3	46.955	50.07	3.1155
11	50	Unbiased-50k	45.658	46.253	0.5941
12	50	Unbiased-50k	45.681	46.367	0.6853
13	50	Unbiased-50k	46.462	46.059	-0.402
14	50	Unbiased-50k	45.882	45.017	-0.8656
16	50	Unbiased-50k	45.889	46.181	0.2922
17	60	Biased-50k	45.486	46.703	1.2166
18	60	Biased-50k	45.729	45.5	-0.2294
19	60	Biased-50k	46.079	46.592	0.5128
20	60	Biased-50k	45.51	46.633	1.1229
21	60	Biased-50k	46.236	46.418	0.1818
24	100	Unbiased-100k	47.886	46.739	-1.1472
25	100	Unbiased-100k	47.838	46.163	-1.6749
26	100	Unbiased-100k	47.175	46.327	-0.8482
27	100	Unbiased-100k	47.255	46.416	-0.8384
28	100	Unbiased-100k	47.415	46.17	-1.2453
29	110	Biased-100k	47.391	46.134	-1.2571
30	110	Biased-100k	46.747	45.79	-0.9576
31	110	Biased-100k	48.432	46.368	-2.064
32	110	Biased-100k	47.262	45.366	-1.8962
34	110	Biased-100k	47.581	46.138	-1.4423

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.705	47.03	47.429	0.36786	46.993	48.356	50.07	1.5685	0.2881	1.326	3.1155	1.5564
50	45.658	45.915	46.462	0.32435	45.017	45.975	46.367	0.54742	-0.8656	0.0608	0.6853	0.67089
60	45.486	45.808	46.236	0.33749	45.5	46.369	46.703	0.49711	-0.2294	0.56094	1.2166	0.61571
100	47.175	47.514	47.886	0.33006	46.163	46.363	46.739	0.23602	-1.6749	-1.1508	-0.8384	0.3438
110	46.747	47.483	48.432	0.61418	45.366	45.959	46.368	0.39079	-2.064	-1.5234	-0.9576	0.45521

Device Test: 53.4 R_LS_7V_25C(LsRdson|LowSide/SW4/7/7/0.5//90.9/634//1.8///@R_LS_7V_25C)





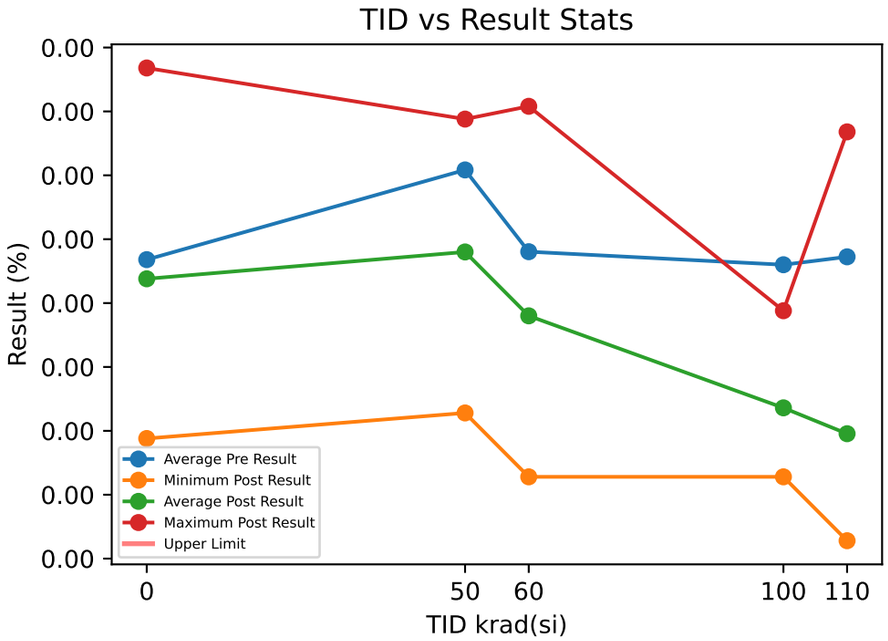
Test Results (Upper Limit = 63.0 (mΩ))

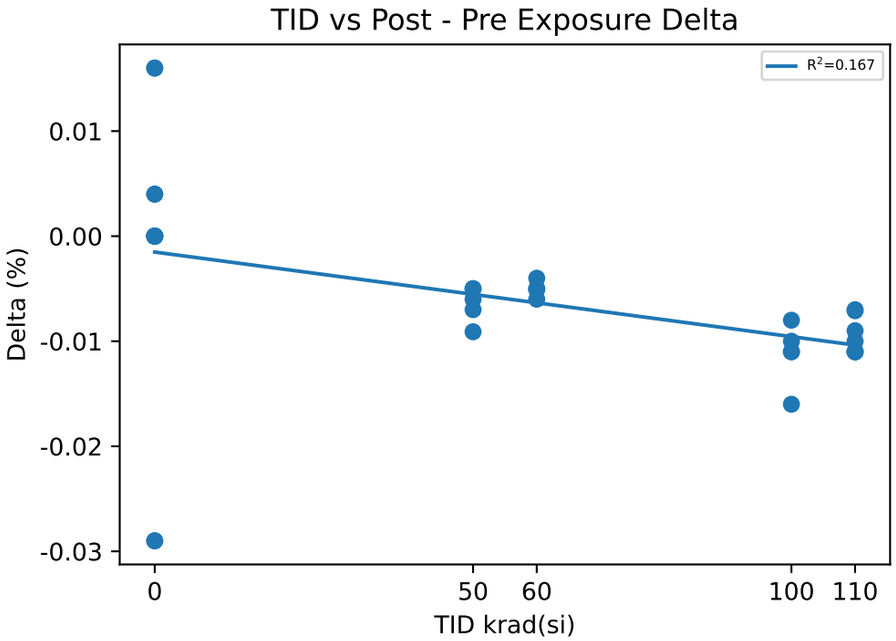
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	50.419	48.373	-2.0453
2	0	CU2	46.691	45.622	-1.0686
3	0	CU3	46.661	46.554	-0.1075
11	50	Unbiased-50k	46.634	45.007	-1.6268
12	50	Unbiased-50k	45.941	44.09	-1.8501
13	50	Unbiased-50k	46.893	43.051	-3.8416
14	50	Unbiased-50k	46.073	43.844	-2.2294
16	50	Unbiased-50k	46.737	44.472	-2.2647
17	60	Biased-50k	46.9	44.193	-2.7077
18	60	Biased-50k	47.525	44.083	-3.4421
19	60	Biased-50k	46.53	45.298	-1.2324
20	60	Biased-50k	45.794	42.792	-3.0019
21	60	Biased-50k	46.825	44.392	-2.4329
24	100	Unbiased-100k	46.444	43.866	-2.5785
25	100	Unbiased-100k	46.658	43.39	-3.2682
26	100	Unbiased-100k	45.443	42.97	-2.4732
27	100	Unbiased-100k	46.312	43.559	-2.7523
28	100	Unbiased-100k	46.626	43.642	-2.9841
29	110	Biased-100k	46.868	43.605	-3.2627
30	110	Biased-100k	46.144	43.49	-2.6537
31	110	Biased-100k	46.933	43.081	-3.8526
32	110	Biased-100k	46.9	43.025	-3.8748
34	110	Biased-100k	46.738	42.807	-3.9308

Test Statistics (mΩ)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.661	47.923	50.419	2.161	45.622	46.85	48.373	1.3994	-2.0453	-1.0738	-0.1075	0.96891
50	45.941	46.455	46.893	0.4224	43.051	44.093	45.007	0.72934	-3.8416	-2.3625	-1.6268	0.86874
60	45.794	46.715	47.525	0.62945	42.792	44.152	45.298	0.89795	-3.4421	-2.5634	-1.2324	0.83274
100	45.443	46.297	46.658	0.49757	42.97	43.485	43.866	0.33537	-3.2682	-2.8113	-2.4732	0.32039
110	46.144	46.717	46.933	0.32865	42.807	43.202	43.605	0.33444	-3.9308	-3.5149	-2.6537	0.55268

Device Test: 54.2 EN_VTH_SEQ_RISING(EnSeqThreshold|RISE/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_RISING





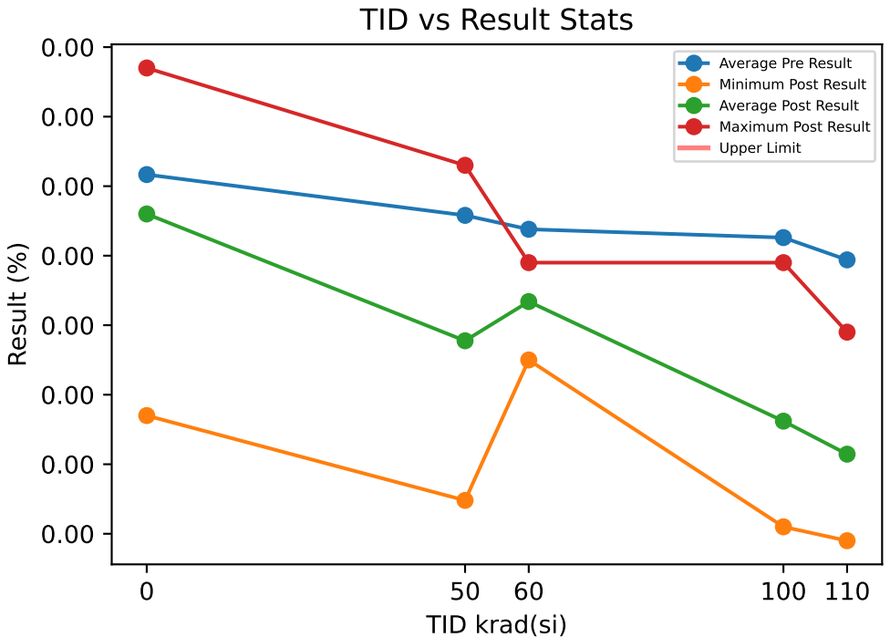
Test Results (No Limits Specified (%))

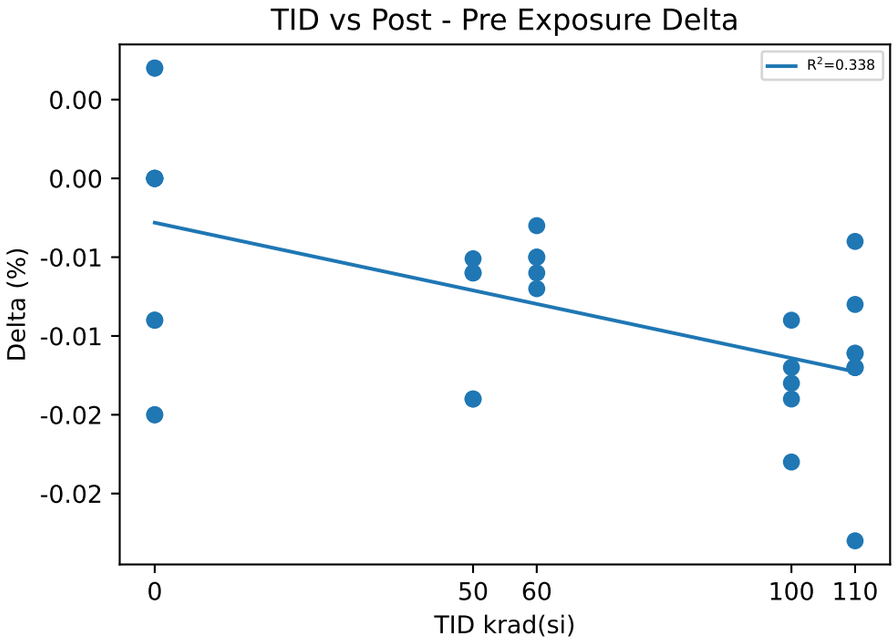
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.944e-13	6.944e-13	0
2	0	CU2	7.234e-13	7.234e-13	0
3	0	CU3	7.074e-13	7.074e-13	0
11	50	Unbiased-50k	7.255e-13	7.164e-13	-0.0091
12	50	Unbiased-50k	7.094e-13	7.024e-13	-0.007
13	50	Unbiased-50k	7.154e-13	7.104e-13	-0.005
14	50	Unbiased-50k	7.024e-13	6.964e-13	-0.006
16	50	Unbiased-50k	7.244e-13	7.194e-13	-0.005
17	60	Biased-50k	7.114e-13	7.064e-13	-0.005
18	60	Biased-50k	7.114e-13	7.054e-13	-0.006
19	60	Biased-50k	7.255e-13	7.204e-13	-0.0051
20	60	Biased-50k	6.954e-13	6.914e-13	-0.004
21	60	Biased-50k	7.014e-13	6.964e-13	-0.005
24	100	Unbiased-100k	7.064e-13	6.954e-13	-0.011
25	100	Unbiased-100k	7.164e-13	7.004e-13	-0.016
26	100	Unbiased-100k	7.144e-13	7.044e-13	-0.01
27	100	Unbiased-100k	7.004e-13	6.924e-13	-0.008
28	100	Unbiased-100k	7.024e-13	6.914e-13	-0.011
29	110	Biased-100k	7.054e-13	6.984e-13	-0.007
30	110	Biased-100k	7.255e-13	7.184e-13	-0.0071
31	110	Biased-100k	7.094e-13	7.004e-13	-0.009
32	110	Biased-100k	7.054e-13	6.954e-13	-0.01
34	110	Biased-100k	6.974e-13	6.864e-13	-0.011

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.944e-13	7.084e-13	7.234e-13	1.4526e-14	6.944e-13	7.084e-13	7.234e-13	1.4526e-14	0	0	0	0
50	7.024e-13	7.1542e-13	7.255e-13	9.849e-15	6.964e-13	7.09e-13	7.194e-13	9.5812e-15	-0.0091	-0.00642	-0.005	0.0017123
60	6.954e-13	7.0902e-13	7.255e-13	1.1473e-14	6.914e-13	7.04e-13	7.204e-13	1.1104e-14	-0.006	-0.00502	-0.004	0.00070852
100	7.004e-13	7.08e-13	7.164e-13	7.1274e-15	6.914e-13	6.968e-13	7.044e-13	5.5045e-15	-0.016	-0.0112	-0.008	0.0029496
110	6.974e-13	7.0862e-13	7.255e-13	1.0394e-14	6.864e-13	6.998e-13	7.184e-13	1.1696e-14	-0.011	-0.00882	-0.007	0.0017641

evice Test: 54.3 EN_VTH_SEQ_FALLING(EnSeqThreshold|FALL/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_FALLIN





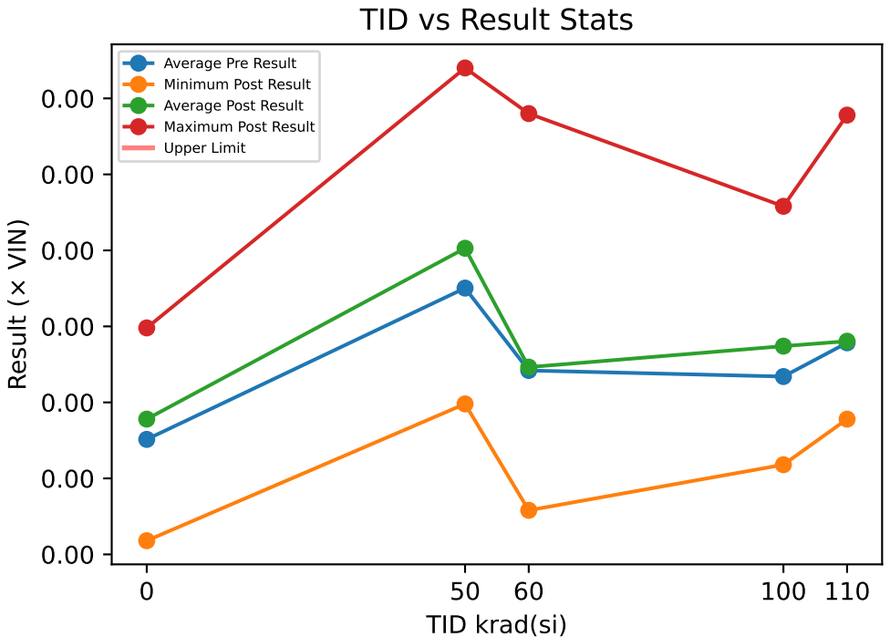
Test Results (No Limits Specified (%))

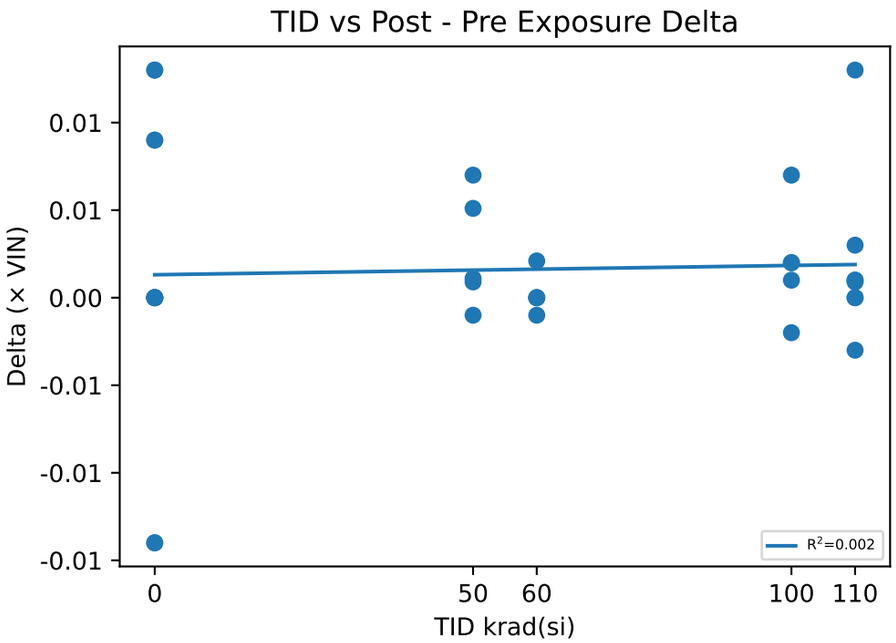
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.475e-13	2.475e-13	0
2	0	CU2	2.635e-13	2.635e-13	0
3	0	CU3	2.565e-13	2.565e-13	0
11	50	Unbiased-50k	2.705e-13	2.565e-13	-0.014
12	50	Unbiased-50k	2.615e-13	2.475e-13	-0.014
13	50	Unbiased-50k	2.465e-13	2.405e-13	-0.006
14	50	Unbiased-50k	2.375e-13	2.324e-13	-0.0051
16	50	Unbiased-50k	2.485e-13	2.425e-13	-0.006
17	60	Biased-50k	2.545e-13	2.495e-13	-0.005
18	60	Biased-50k	2.525e-13	2.465e-13	-0.006
19	60	Biased-50k	2.535e-13	2.465e-13	-0.007
20	60	Biased-50k	2.455e-13	2.425e-13	-0.003
21	60	Biased-50k	2.535e-13	2.485e-13	-0.005
24	100	Unbiased-100k	2.435e-13	2.305e-13	-0.013
25	100	Unbiased-100k	2.635e-13	2.495e-13	-0.014
26	100	Unbiased-100k	2.485e-13	2.365e-13	-0.012
27	100	Unbiased-100k	2.465e-13	2.375e-13	-0.009
28	100	Unbiased-100k	2.545e-13	2.365e-13	-0.018
29	110	Biased-100k	2.475e-13	2.435e-13	-0.004
30	110	Biased-100k	2.525e-13	2.445e-13	-0.008
31	110	Biased-100k	2.525e-13	2.405e-13	-0.012
32	110	Biased-100k	2.525e-13	2.295e-13	-0.023
34	110	Biased-100k	2.435e-13	2.315e-13	-0.012

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.475e-13	2.5583e-13	2.635e-13	8.0208e-15	2.475e-13	2.5583e-13	2.635e-13	8.0208e-15	0	0	0	0
50	2.375e-13	2.529e-13	2.705e-13	1.305e-14	2.324e-13	2.4388e-13	2.565e-13	8.9091e-15	-0.014	-0.00902	-0.0051	0.0045609
60	2.455e-13	2.519e-13	2.545e-13	3.6469e-15	2.425e-13	2.467e-13	2.495e-13	2.6833e-15	-0.007	-0.0052	-0.003	0.0014832
100	2.435e-13	2.513e-13	2.635e-13	7.9183e-15	2.305e-13	2.381e-13	2.495e-13	6.9498e-15	-0.018	-0.0132	-0.009	0.0032711
110	2.435e-13	2.497e-13	2.525e-13	4.0866e-15	2.295e-13	2.379e-13	2.445e-13	6.9498e-15	-0.023	-0.0118	-0.004	0.0070852

Device Test: 54.4 EN_VTH_SEQ_HYST(EnSeqThreshold|HYST/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_HYST)





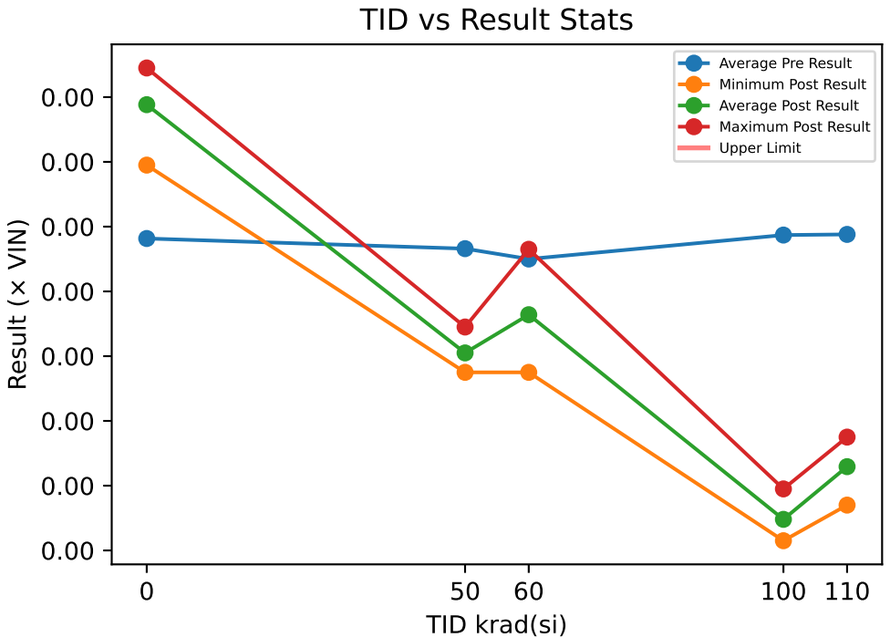
Test Results (No Limits Specified (× VIN))

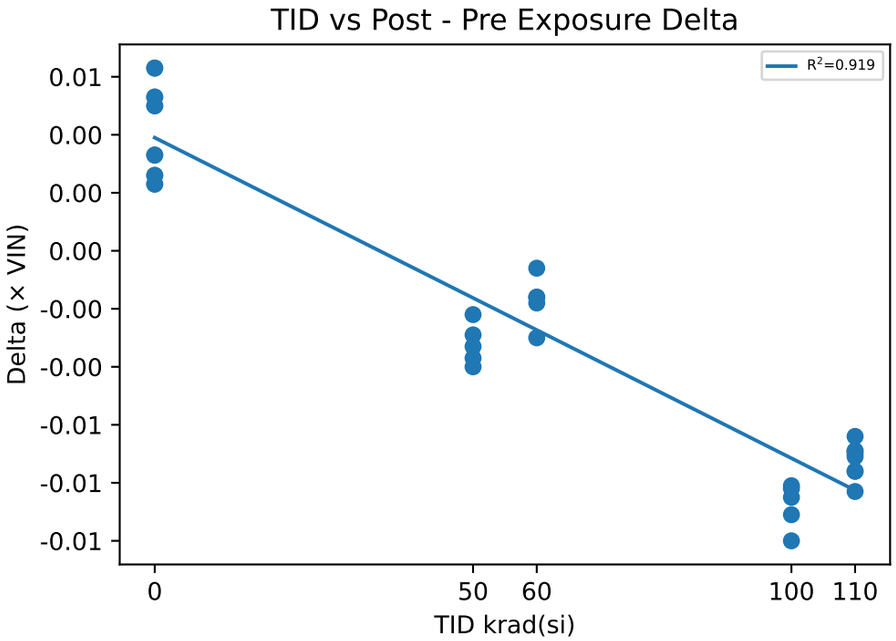
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	4.469e-13	4.469e-13	0
2	0	CU2	4.599e-13	4.599e-13	0
3	0	CU3	4.509e-13	4.509e-13	0
11	50	Unbiased-50k	4.549e-13	4.6e-13	0.0051
12	50	Unbiased-50k	4.479e-13	4.549e-13	0.007
13	50	Unbiased-50k	4.69e-13	4.699e-13	0.0009
14	50	Unbiased-50k	4.649e-13	4.639e-13	-0.001
16	50	Unbiased-50k	4.759e-13	4.77e-13	0.0011
17	60	Biased-50k	4.569e-13	4.569e-13	0
18	60	Biased-50k	4.589e-13	4.589e-13	0
19	60	Biased-50k	4.719e-13	4.74e-13	0.0021
20	60	Biased-50k	4.499e-13	4.489e-13	-0.001
21	60	Biased-50k	4.479e-13	4.479e-13	0
24	100	Unbiased-100k	4.629e-13	4.649e-13	0.002
25	100	Unbiased-100k	4.529e-13	4.509e-13	-0.002
26	100	Unbiased-100k	4.659e-13	4.679e-13	0.002
27	100	Unbiased-100k	4.539e-13	4.549e-13	0.001
28	100	Unbiased-100k	4.479e-13	4.549e-13	0.007
29	110	Biased-100k	4.579e-13	4.549e-13	-0.003
30	110	Biased-100k	4.73e-13	4.739e-13	0.0009
31	110	Biased-100k	4.569e-13	4.599e-13	0.003
32	110	Biased-100k	4.529e-13	4.659e-13	0.013
34	110	Biased-100k	4.539e-13	4.549e-13	0.001

Test Statistics (× VIN)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.469e-13	4.5257e-13	4.599e-13	6.6583e-15	4.469e-13	4.5257e-13	4.599e-13	6.6583e-15	0	0	0	0
50	4.479e-13	4.6252e-13	4.759e-13	1.1163e-14	4.549e-13	4.6514e-13	4.77e-13	8.6042e-15	-0.001	0.00262	0.007	0.0033056
60	4.479e-13	4.571e-13	4.719e-13	9.471e-15	4.479e-13	4.5732e-13	4.74e-13	1.0494e-14	-0.001	0.00022	0.0021	0.0011367
100	4.479e-13	4.567e-13	4.659e-13	7.4632e-15	4.509e-13	4.587e-13	4.679e-13	7.2938e-15	-0.002	0.002	0.007	0.0032404
110	4.529e-13	4.5892e-13	4.73e-13	8.1365e-15	4.549e-13	4.619e-13	4.739e-13	8.0932e-15	-0.003	0.00298	0.013	0.0060085

Device Test: 54.5 EN_VTH_SEQ_OPEN(EnSeqThreshold|OPEN/EN_SEQ/5/5///511/1020//1.8///@EN_VTH_SEQ_OPEN)





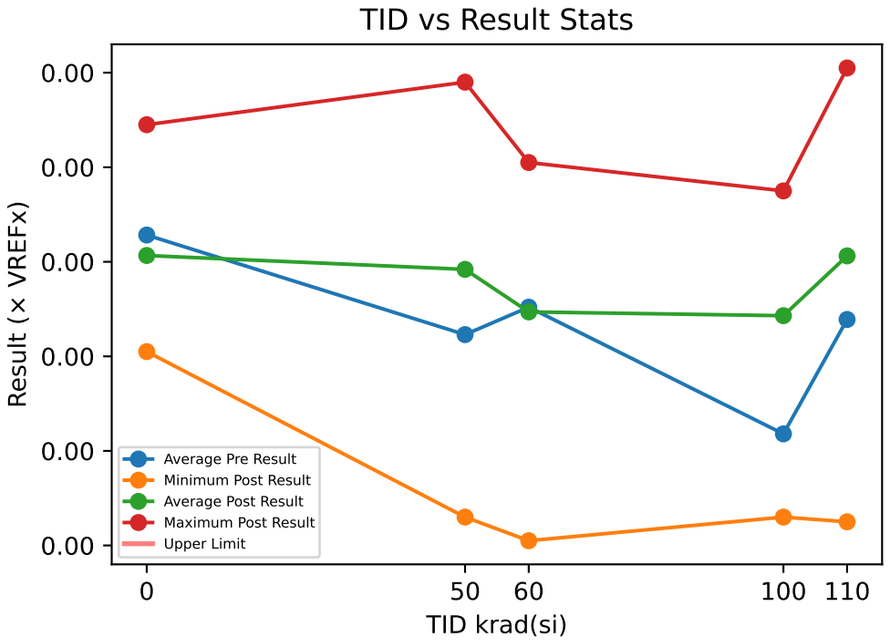
Test Results (No Limits Specified (× VIN))

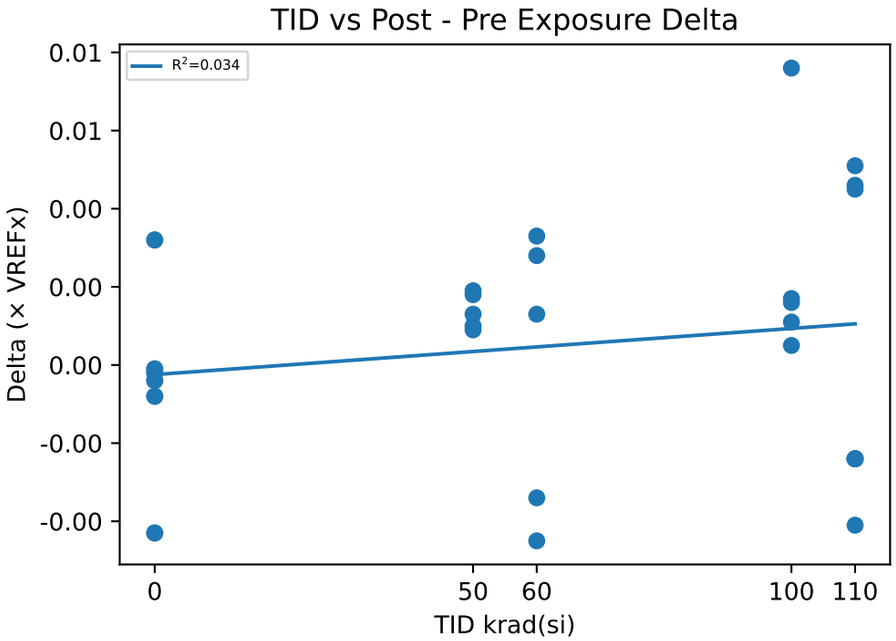
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	4.812e-13	4.845e-13	0.0033
2	0	CU2	4.781e-13	4.831e-13	0.005
3	0	CU3	4.796e-13	4.849e-13	0.0053
11	50	Unbiased-50k	4.78e-13	4.758e-13	-0.0022
12	50	Unbiased-50k	4.788e-13	4.755e-13	-0.0033
13	50	Unbiased-50k	4.797e-13	4.757e-13	-0.004
14	50	Unbiased-50k	4.806e-13	4.769e-13	-0.0037
16	50	Unbiased-50k	4.795e-13	4.766e-13	-0.0029
17	60	Biased-50k	4.807e-13	4.777e-13	-0.003
18	60	Biased-50k	4.782e-13	4.766e-13	-0.0016
19	60	Biased-50k	4.771e-13	4.755e-13	-0.0016
20	60	Biased-50k	4.791e-13	4.773e-13	-0.0018
21	60	Biased-50k	4.799e-13	4.793e-13	-0.0006
24	100	Unbiased-100k	4.806e-13	4.706e-13	-0.01
25	100	Unbiased-100k	4.792e-13	4.711e-13	-0.0081
26	100	Unbiased-100k	4.791e-13	4.709e-13	-0.0082
27	100	Unbiased-100k	4.794e-13	4.703e-13	-0.0091
28	100	Unbiased-100k	4.804e-13	4.719e-13	-0.0085
29	110	Biased-100k	4.805e-13	4.735e-13	-0.007
30	110	Biased-100k	4.799e-13	4.728e-13	-0.0071
31	110	Biased-100k	4.797e-13	4.714e-13	-0.0083
32	110	Biased-100k	4.788e-13	4.724e-13	-0.0064
34	110	Biased-100k	4.799e-13	4.73e-13	-0.0069

Test Statistics (× VIN)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.781e-13	4.7963e-13	4.812e-13	1.5503e-15	4.831e-13	4.8417e-13	4.849e-13	9.4516e-16	0.0033	0.0045333	0.0053	0.0010786
50	4.78e-13	4.7932e-13	4.806e-13	9.7826e-16	4.755e-13	4.761e-13	4.769e-13	6.1237e-16	-0.004	-0.00322	-0.0022	0.00070498
60	4.771e-13	4.79e-13	4.807e-13	1.4107e-15	4.755e-13	4.7728e-13	4.793e-13	1.4043e-15	-0.003	-0.00172	-0.0006	0.00085557
100	4.791e-13	4.7974e-13	4.806e-13	7.0569e-16	4.703e-13	4.7096e-13	4.719e-13	6.0663e-16	-0.01	-0.00878	-0.0081	0.00078549
110	4.788e-13	4.7976e-13	4.805e-13	6.1482e-16	4.714e-13	4.7262e-13	4.735e-13	7.8867e-16	-0.0083	-0.00714	-0.0064	0.00070214

Device Test: 55.1 V_CHANNEL_ON(EnSeq|PowerUp/VS1_to_COMP2/3/3///90.9/634//1.8//12/@V_CHANNEL_ON)





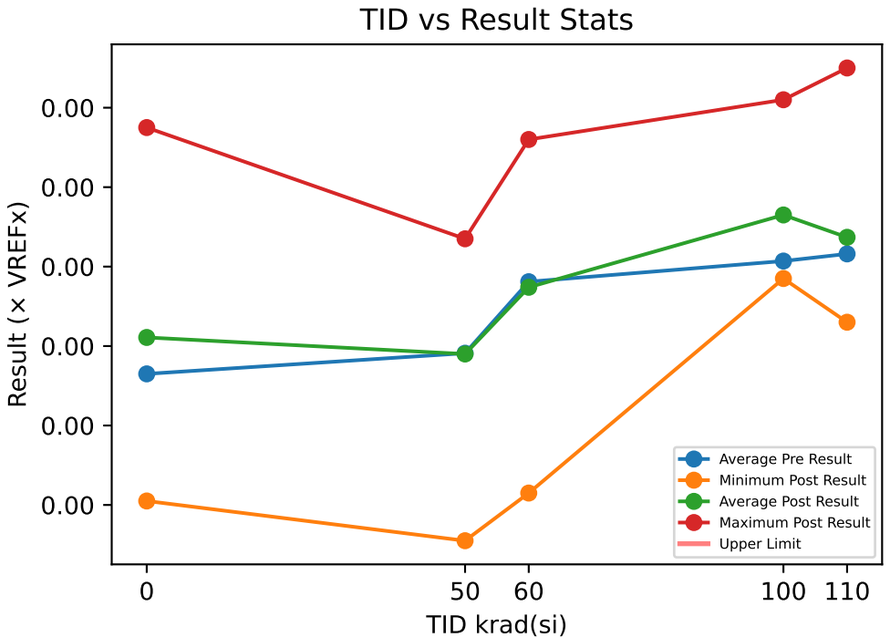
Test Results (No Limits Specified (× VREFx))

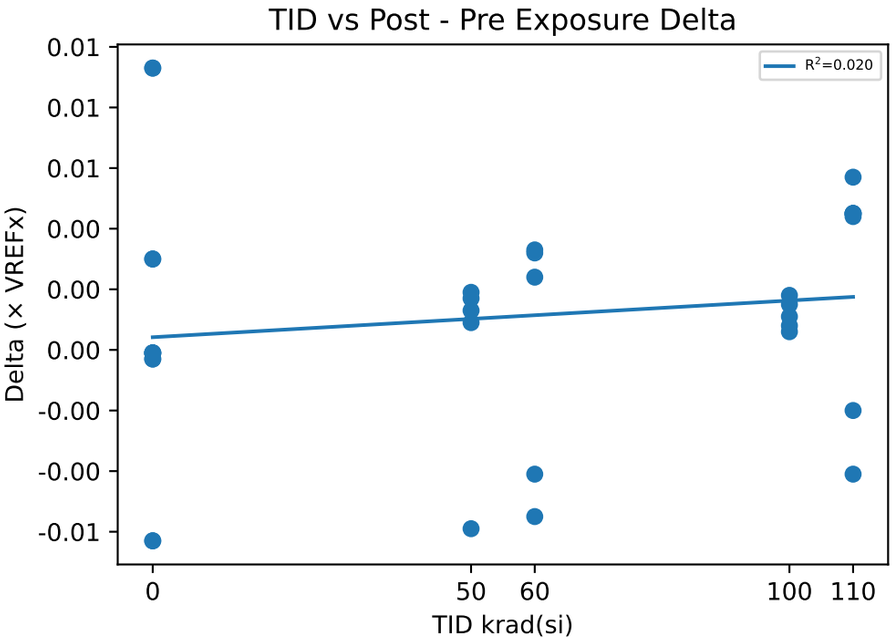
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.509e-13	8.508e-13	-0.0001
2	0	CU2	8.551e-13	8.549e-13	-0.0002
3	0	CU3	8.517e-13	8.513e-13	-0.0004
11	50	Unbiased-50k	8.54e-13	8.558e-13	0.0018
12	50	Unbiased-50k	8.499e-13	8.518e-13	0.0019
13	50	Unbiased-50k	8.51e-13	8.519e-13	0.0009
14	50	Unbiased-50k	8.521e-13	8.531e-13	0.001
16	50	Unbiased-50k	8.453e-13	8.466e-13	0.0013
17	60	Biased-50k	8.506e-13	8.461e-13	-0.0045
18	60	Biased-50k	8.536e-13	8.502e-13	-0.0034
19	60	Biased-50k	8.51e-13	8.538e-13	0.0028
20	60	Biased-50k	8.508e-13	8.541e-13	0.0033
21	60	Biased-50k	8.492e-13	8.505e-13	0.0013
24	100	Unbiased-100k	8.519e-13	8.535e-13	0.0016
25	100	Unbiased-100k	8.509e-13	8.52e-13	0.0011
26	100	Unbiased-100k	8.488e-13	8.505e-13	0.0017
27	100	Unbiased-100k	8.461e-13	8.466e-13	0.0005
28	100	Unbiased-100k	8.441e-13	8.517e-13	0.0076
29	110	Biased-100k	8.516e-13	8.561e-13	0.0045
30	110	Biased-100k	8.506e-13	8.465e-13	-0.0041
31	110	Biased-100k	8.47e-13	8.516e-13	0.0046
32	110	Biased-100k	8.505e-13	8.556e-13	0.0051
34	110	Biased-100k	8.542e-13	8.518e-13	-0.0024

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.509e-13	8.5257e-13	8.551e-13	2.2301e-15	8.508e-13	8.5233e-13	8.549e-13	2.2368e-15	-0.0004	-0.00023333	-0.0001	0.00015275
50	8.453e-13	8.5046e-13	8.54e-13	3.2578e-15	8.466e-13	8.5184e-13	8.558e-13	3.3441e-15	0.0009	0.00138	0.0019	0.00045497
60	8.492e-13	8.5104e-13	8.536e-13	1.5962e-15	8.461e-13	8.5094e-13	8.541e-13	3.2532e-15	-0.0045	-0.0001	0.0033	0.0036118
100	8.441e-13	8.4836e-13	8.519e-13	3.257e-15	8.466e-13	8.5086e-13	8.535e-13	2.6102e-15	0.0005	0.0025	0.0076	0.0028905
110	8.47e-13	8.5078e-13	8.542e-13	2.5869e-15	8.465e-13	8.5232e-13	8.561e-13	3.8635e-15	-0.0041	0.00154	0.0051	0.0044196

Device Test: 55.2 V_CHANNEL_ON(EnSeq|PowerUp/VS2_to_COMP3/3/3///90.9/634//1.8//12/@V_CHANNEL_ON)





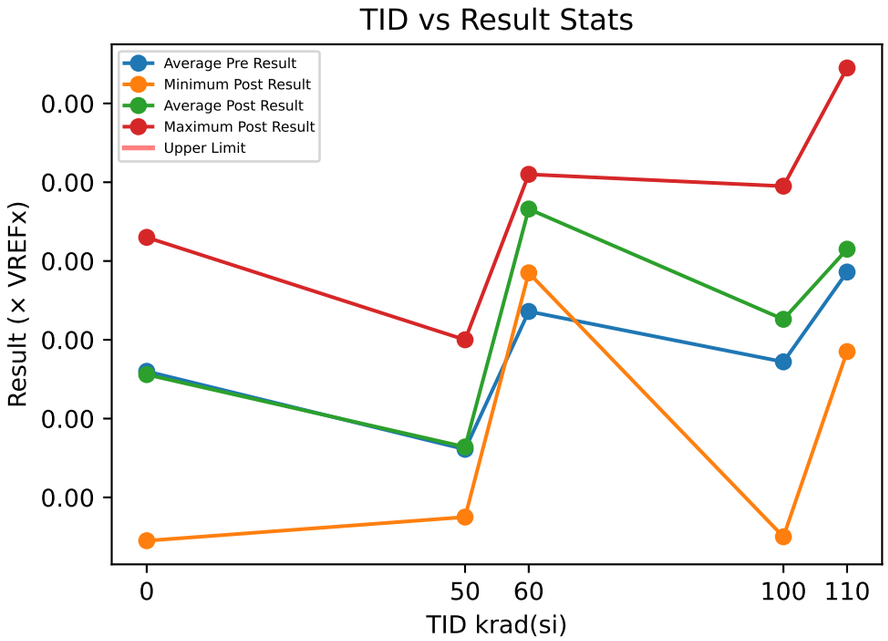
Test Results (No Limits Specified (× VREFx))

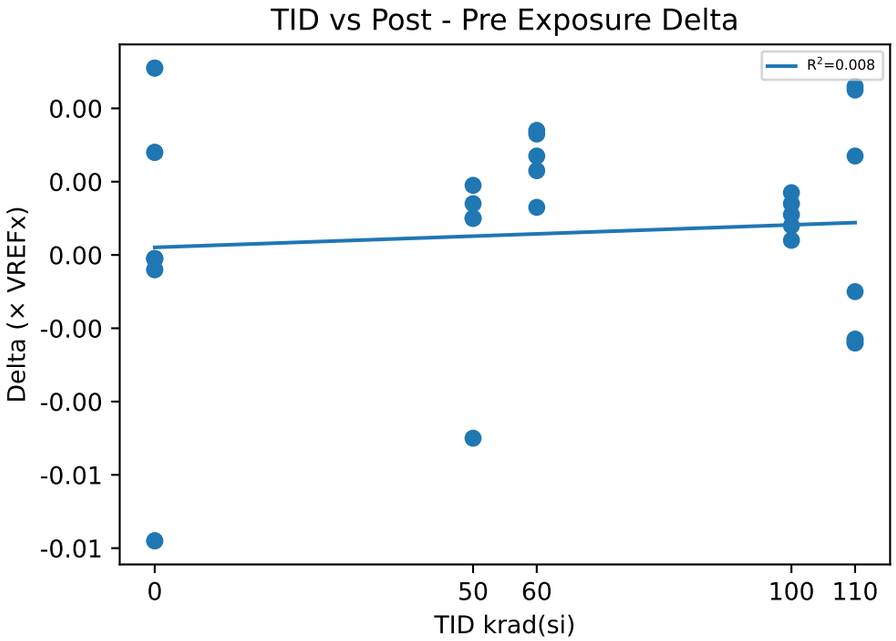
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.462e-13	8.461e-13	-0.0001
2	0	CU2	8.524e-13	8.523e-13	-0.0001
3	0	CU3	8.493e-13	8.49e-13	-0.0003
11	50	Unbiased-50k	8.474e-13	8.491e-13	0.0017
12	50	Unbiased-50k	8.508e-13	8.527e-13	0.0019
13	50	Unbiased-50k	8.504e-13	8.513e-13	0.0009
14	50	Unbiased-50k	8.51e-13	8.451e-13	-0.0059
16	50	Unbiased-50k	8.495e-13	8.508e-13	0.0013
17	60	Biased-50k	8.497e-13	8.521e-13	0.0024
18	60	Biased-50k	8.519e-13	8.552e-13	0.0033
19	60	Biased-50k	8.504e-13	8.463e-13	-0.0041
20	60	Biased-50k	8.494e-13	8.526e-13	0.0032
21	60	Biased-50k	8.567e-13	8.512e-13	-0.0055
24	100	Unbiased-100k	8.519e-13	8.534e-13	0.0015
25	100	Unbiased-100k	8.506e-13	8.517e-13	0.0011
26	100	Unbiased-100k	8.511e-13	8.529e-13	0.0018
27	100	Unbiased-100k	8.556e-13	8.562e-13	0.0006
28	100	Unbiased-100k	8.515e-13	8.523e-13	0.0008
29	110	Biased-100k	8.524e-13	8.568e-13	0.0044
30	110	Biased-100k	8.573e-13	8.532e-13	-0.0041
31	110	Biased-100k	8.545e-13	8.525e-13	-0.002
32	110	Biased-100k	8.513e-13	8.57e-13	0.0057
34	110	Biased-100k	8.461e-13	8.506e-13	0.0045

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.462e-13	8.493e-13	8.524e-13	3.1e-15	8.461e-13	8.4913e-13	8.523e-13	3.1021e-15	-0.0003	-0.00016667	-0.0001	0.00011547
50	8.474e-13	8.4982e-13	8.51e-13	1.4704e-15	8.451e-13	8.498e-13	8.527e-13	2.9257e-15	-0.0059	-2e-05	0.0019	0.0033094
60	8.494e-13	8.5162e-13	8.567e-13	2.9995e-15	8.463e-13	8.5148e-13	8.552e-13	3.2553e-15	-0.0055	-0.00014	0.0033	0.0042969
100	8.506e-13	8.5214e-13	8.556e-13	1.9932e-15	8.517e-13	8.533e-13	8.562e-13	1.7421e-15	0.0006	0.00116	0.0018	0.00049295
110	8.461e-13	8.5232e-13	8.573e-13	4.162e-15	8.506e-13	8.5402e-13	8.57e-13	2.7968e-15	-0.0041	0.0017	0.0057	0.0044289

Device Test: 55.3 V_CHANNEL_ON(EnSeq|PowerUp/VS3_to_COMP4/3/3///90.9/634//1.8//12/@V_CHANNEL_ON)





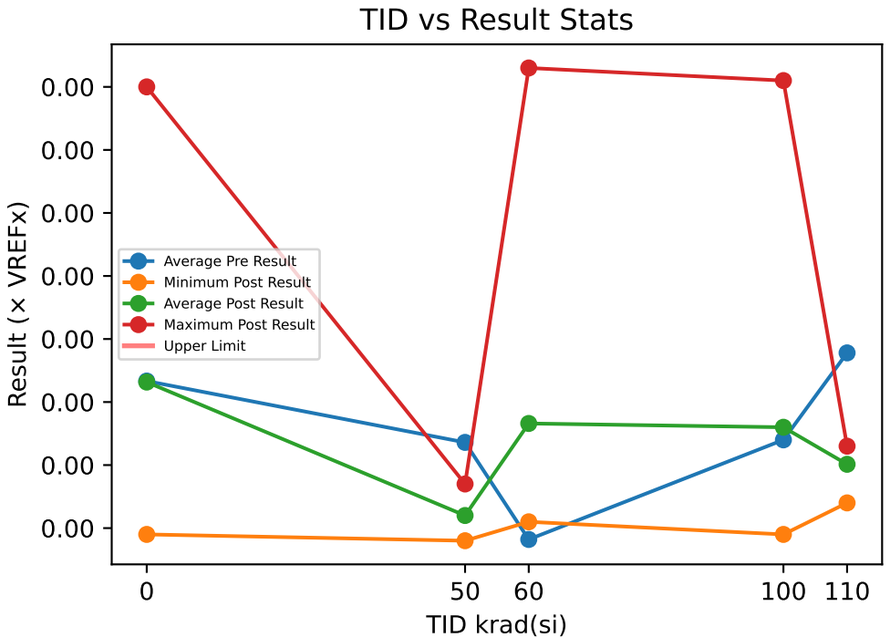
Test Results (No Limits Specified (× VREFx))

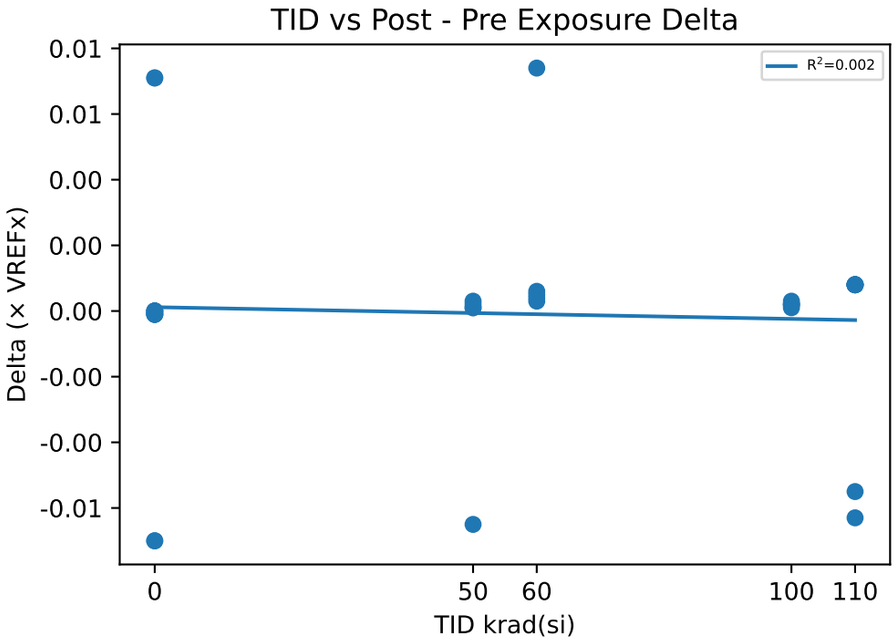
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.451e-13	8.45e-13	-0.0001
2	0	CU2	8.527e-13	8.526e-13	-0.0001
3	0	CU3	8.498e-13	8.494e-13	-0.0004
11	50	Unbiased-50k	8.535e-13	8.485e-13	-0.005
12	50	Unbiased-50k	8.445e-13	8.464e-13	0.0019
13	50	Unbiased-50k	8.49e-13	8.5e-13	0.001
14	50	Unbiased-50k	8.445e-13	8.455e-13	0.001
16	50	Unbiased-50k	8.446e-13	8.46e-13	0.0014
17	60	Biased-50k	8.517e-13	8.54e-13	0.0023
18	60	Biased-50k	8.508e-13	8.542e-13	0.0034
19	60	Biased-50k	8.5e-13	8.527e-13	0.0027
20	60	Biased-50k	8.507e-13	8.54e-13	0.0033
21	60	Biased-50k	8.504e-13	8.517e-13	0.0013
24	100	Unbiased-100k	8.513e-13	8.527e-13	0.0014
25	100	Unbiased-100k	8.528e-13	8.539e-13	0.0011
26	100	Unbiased-100k	8.433e-13	8.45e-13	0.0017
27	100	Unbiased-100k	8.472e-13	8.476e-13	0.0004
28	100	Unbiased-100k	8.526e-13	8.534e-13	0.0008
29	110	Biased-100k	8.52e-13	8.565e-13	0.0045
30	110	Biased-100k	8.508e-13	8.535e-13	0.0027
31	110	Biased-100k	8.523e-13	8.569e-13	0.0046
32	110	Biased-100k	8.507e-13	8.497e-13	-0.001
34	110	Biased-100k	8.528e-13	8.504e-13	-0.0024

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.451e-13	8.492e-13	8.527e-13	3.8354e-15	8.45e-13	8.49e-13	8.526e-13	3.8158e-15	-0.0004	-0.0002	-0.0001	0.00017321
50	8.445e-13	8.4722e-13	8.535e-13	4.0084e-15	8.455e-13	8.4728e-13	8.5e-13	1.9018e-15	-0.005	6e-05	0.0019	0.0028527
60	8.5e-13	8.5072e-13	8.517e-13	6.3008e-16	8.517e-13	8.5332e-13	8.542e-13	1.0849e-15	0.0013	0.0026	0.0034	0.0008544
100	8.433e-13	8.4944e-13	8.528e-13	4.1065e-15	8.45e-13	8.5052e-13	8.539e-13	3.9833e-15	0.0004	0.00108	0.0017	0.00050695
110	8.507e-13	8.5172e-13	8.528e-13	9.3113e-16	8.497e-13	8.534e-13	8.569e-13	3.3377e-15	-0.0024	0.00168	0.0046	0.0032151

Device Test: 55.4 V_CHANNEL_OFF(EnSeq|PowerDown/VS4_to_COMP3/3/3///90.9/634//1.8//12/@V_CHANNEL_OFF)





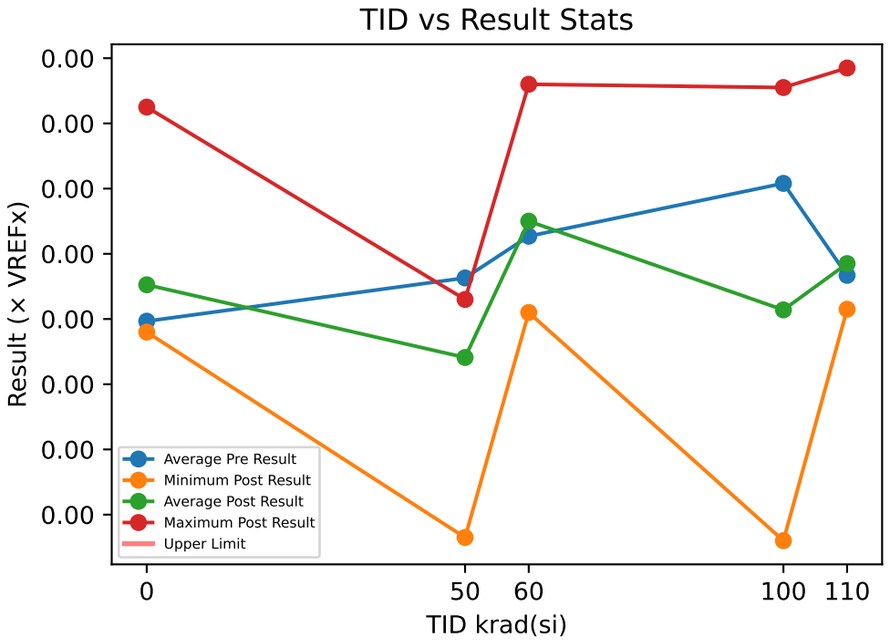
Test Results (No Limits Specified (× VREFx))

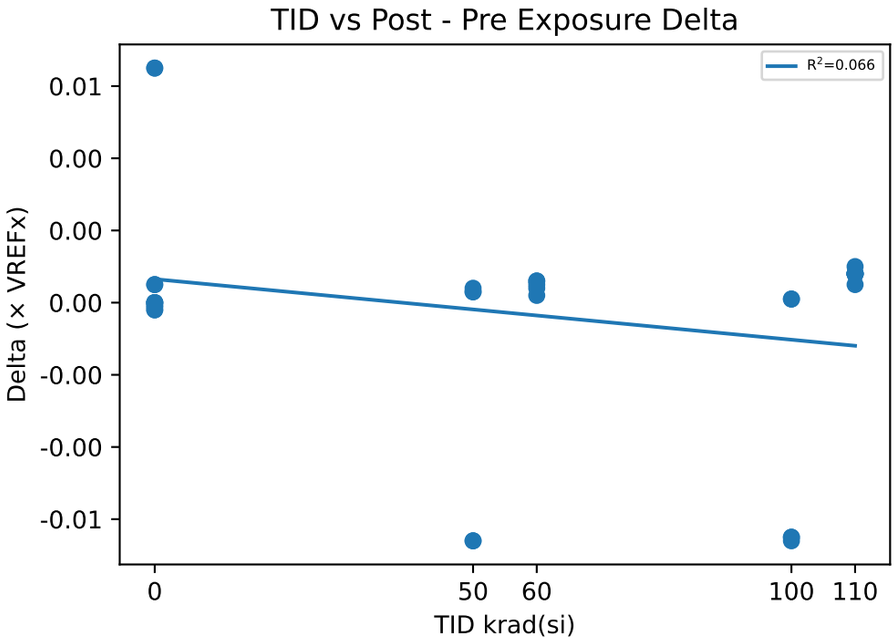
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.501e-13	1.5e-13	-0.0001
2	0	CU2	1.57e-13	1.57e-13	0
3	0	CU3	1.499e-13	1.499e-13	0
11	50	Unbiased-50k	1.504e-13	1.507e-13	0.0003
12	50	Unbiased-50k	1.566e-13	1.501e-13	-0.0065
13	50	Unbiased-50k	1.497e-13	1.498e-13	0.0001
14	50	Unbiased-50k	1.501e-13	1.502e-13	0.0001
16	50	Unbiased-50k	1.5e-13	1.502e-13	0.0002
17	60	Biased-50k	1.497e-13	1.501e-13	0.0004
18	60	Biased-50k	1.499e-13	1.505e-13	0.0006
19	60	Biased-50k	1.498e-13	1.503e-13	0.0005
20	60	Biased-50k	1.499e-13	1.573e-13	0.0074
21	60	Biased-50k	1.498e-13	1.501e-13	0.0003
24	100	Unbiased-100k	1.501e-13	1.503e-13	0.0002
25	100	Unbiased-100k	1.497e-13	1.499e-13	0.0002
26	100	Unbiased-100k	1.499e-13	1.502e-13	0.0003
27	100	Unbiased-100k	1.504e-13	1.505e-13	0.0001
28	100	Unbiased-100k	1.569e-13	1.571e-13	0.0002
29	110	Biased-100k	1.5e-13	1.508e-13	0.0008
30	110	Biased-100k	1.567e-13	1.504e-13	-0.0063
31	110	Biased-100k	1.505e-13	1.513e-13	0.0008
32	110	Biased-100k	1.563e-13	1.508e-13	-0.0055
34	110	Biased-100k	1.504e-13	1.512e-13	0.0008

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.499e-13	1.5233e-13	1.57e-13	4.0427e-15	1.499e-13	1.523e-13	1.57e-13	4.0706e-15	-0.0001	-3.3333e-05	0	5.7735e-05
50	1.497e-13	1.5136e-13	1.566e-13	2.9399e-15	1.498e-13	1.502e-13	1.507e-13	3.2404e-16	-0.0065	-0.00116	0.0003	0.0029863
60	1.497e-13	1.4982e-13	1.499e-13	8.3666e-17	1.501e-13	1.5166e-13	1.573e-13	3.1572e-15	0.0003	0.00184	0.0074	0.0031101
100	1.497e-13	1.514e-13	1.569e-13	3.0854e-15	1.499e-13	1.516e-13	1.571e-13	3.0822e-15	0.0001	0.0002	0.0003	7.0711e-05
110	1.5e-13	1.5278e-13	1.567e-13	3.404e-15	1.504e-13	1.509e-13	1.513e-13	3.6056e-16	-0.0063	-0.00188	0.0008	0.0036806

Device Test: 55.5 V_CHANNEL_OFF(EnSeq|PowerDown/VS3_to_COMP2/3/3///90.9/634//1.8//12/@V_CHANNEL_OFF)





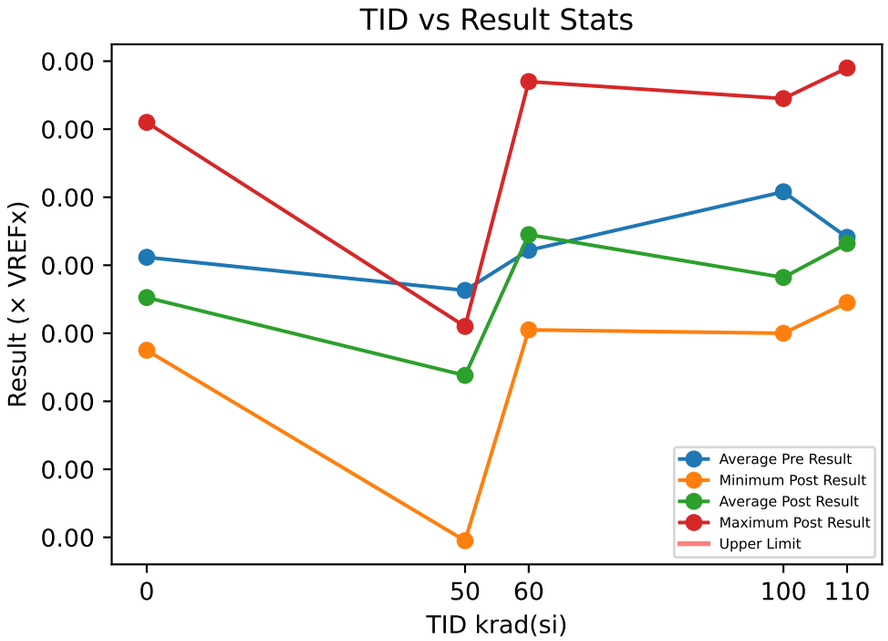
Test Results (No Limits Specified (× VREFx))

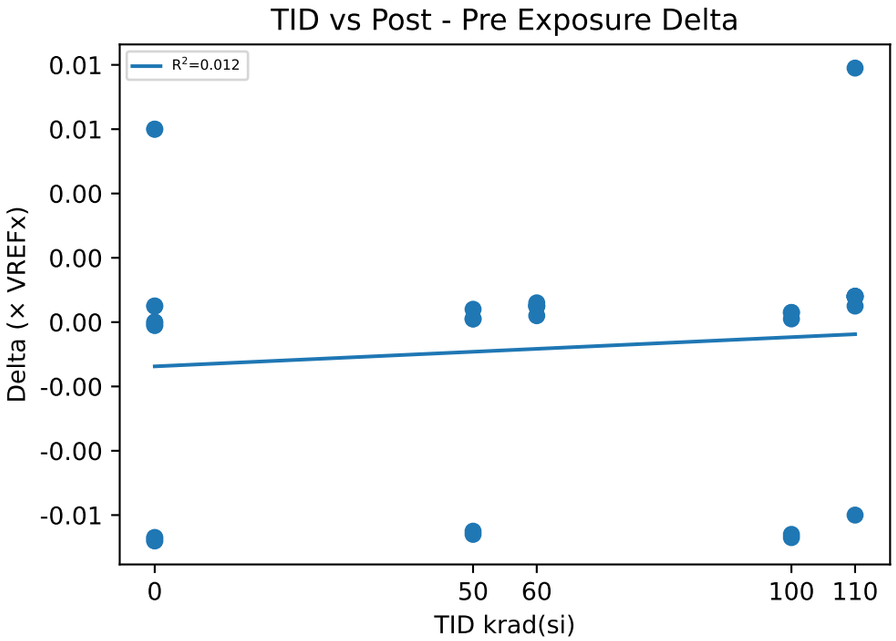
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.5e-13	1.5e-13	0
2	0	CU2	1.502e-13	1.501e-13	-0.0001
3	0	CU3	1.496e-13	1.496e-13	0
11	50	Unbiased-50k	1.503e-13	1.506e-13	0.0003
12	50	Unbiased-50k	1.499e-13	1.503e-13	0.0004
13	50	Unbiased-50k	1.563e-13	1.497e-13	-0.0066
14	50	Unbiased-50k	1.499e-13	1.433e-13	-0.0066
16	50	Unbiased-50k	1.499e-13	1.502e-13	0.0003
17	60	Biased-50k	1.568e-13	1.572e-13	0.0004
18	60	Biased-50k	1.498e-13	1.504e-13	0.0006
19	60	Biased-50k	1.497e-13	1.502e-13	0.0005
20	60	Biased-50k	1.498e-13	1.504e-13	0.0006
21	60	Biased-50k	1.566e-13	1.568e-13	0.0002
24	100	Unbiased-100k	1.567e-13	1.502e-13	-0.0065
25	100	Unbiased-100k	1.57e-13	1.504e-13	-0.0066
26	100	Unbiased-100k	1.497e-13	1.432e-13	-0.0065
27	100	Unbiased-100k	1.504e-13	1.505e-13	0.0001
28	100	Unbiased-100k	1.57e-13	1.571e-13	0.0001
29	110	Biased-100k	1.5e-13	1.508e-13	0.0008
30	110	Biased-100k	1.498e-13	1.503e-13	0.0005
31	110	Biased-100k	1.569e-13	1.577e-13	0.0008
32	110	Biased-100k	1.498e-13	1.508e-13	0.001
34	110	Biased-100k	1.502e-13	1.51e-13	0.0008

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.496e-13	1.4993e-13	1.502e-13	3.0551e-16	1.496e-13	1.499e-13	1.501e-13	2.6458e-16	-0.0001	-3.3333e-05	0	5.7735e-05
50	1.499e-13	1.5126e-13	1.563e-13	2.8228e-15	1.433e-13	1.4882e-13	1.506e-13	3.1027e-15	-0.0066	-0.00244	0.0004	0.0037978
60	1.497e-13	1.5254e-13	1.568e-13	3.7984e-15	1.502e-13	1.53e-13	1.572e-13	3.6551e-15	0.0002	0.00046	0.0006	0.00016733
100	1.497e-13	1.5416e-13	1.57e-13	3.762e-15	1.432e-13	1.5028e-13	1.571e-13	4.917e-15	-0.0066	-0.00388	0.0001	0.0036335
110	1.498e-13	1.5134e-13	1.569e-13	3.1126e-15	1.503e-13	1.5212e-13	1.577e-13	3.13e-15	0.0005	0.00078	0.001	0.00017889

Device Test: 55.6 V_CHANNEL_OFF(EnSeq|PowerDown/VS2_to_COMP1/3/3///90.9/634//1.8//12/@V_CHANNEL_OFF)





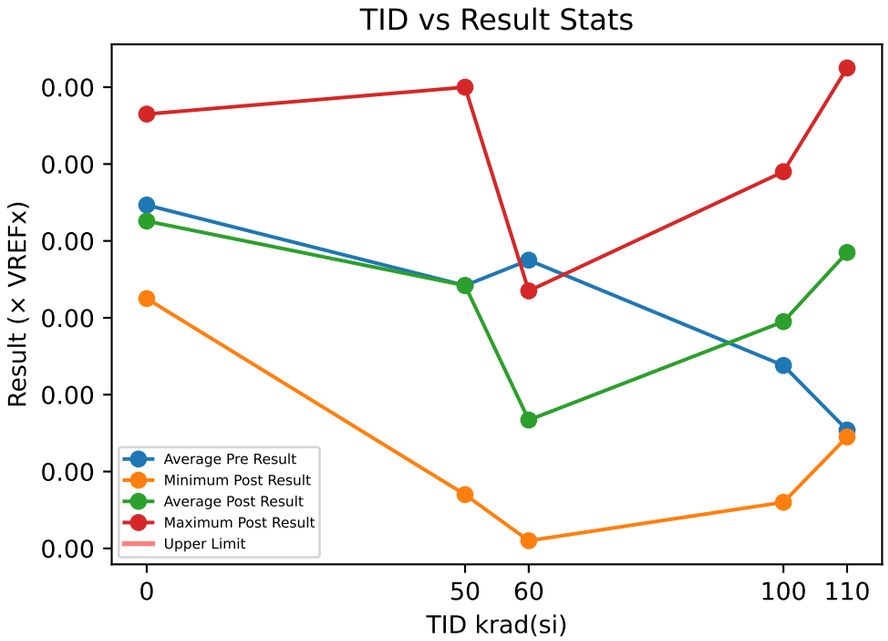
Test Results (No Limits Specified (× VREFx))

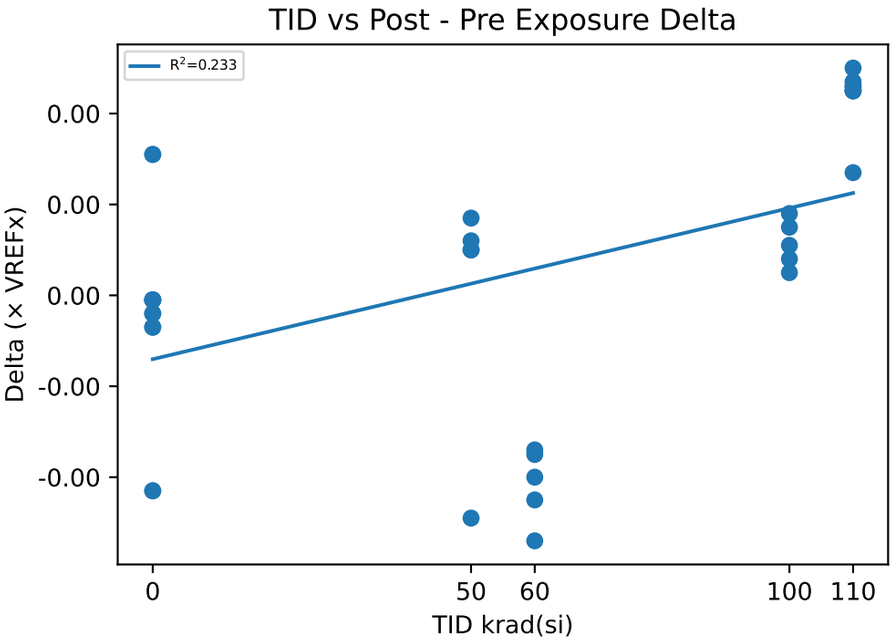
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.502e-13	1.502e-13	0
2	0	CU2	1.569e-13	1.501e-13	-0.0068
3	0	CU3	1.496e-13	1.495e-13	-0.0001
11	50	Unbiased-50k	1.504e-13	1.439e-13	-0.0065
12	50	Unbiased-50k	1.498e-13	1.502e-13	0.0004
13	50	Unbiased-50k	1.498e-13	1.499e-13	0.0001
14	50	Unbiased-50k	1.499e-13	1.5e-13	0.0001
16	50	Unbiased-50k	1.564e-13	1.498e-13	-0.0066
17	60	Biased-50k	1.496e-13	1.501e-13	0.0005
18	60	Biased-50k	1.568e-13	1.574e-13	0.0006
19	60	Biased-50k	1.497e-13	1.502e-13	0.0005
20	60	Biased-50k	1.496e-13	1.501e-13	0.0005
21	60	Biased-50k	1.565e-13	1.567e-13	0.0002
24	100	Unbiased-100k	1.5e-13	1.503e-13	0.0003
25	100	Unbiased-100k	1.566e-13	1.5e-13	-0.0066
26	100	Unbiased-100k	1.499e-13	1.502e-13	0.0003
27	100	Unbiased-100k	1.575e-13	1.508e-13	-0.0067
28	100	Unbiased-100k	1.568e-13	1.569e-13	0.0001
29	110	Biased-100k	1.569e-13	1.509e-13	-0.006
30	110	Biased-100k	1.566e-13	1.571e-13	0.0005
31	110	Biased-100k	1.505e-13	1.513e-13	0.0008
32	110	Biased-100k	1.499e-13	1.578e-13	0.0079
34	110	Biased-100k	1.502e-13	1.51e-13	0.0008

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.496e-13	1.5223e-13	1.569e-13	4.0526e-15	1.495e-13	1.4993e-13	1.502e-13	3.7859e-16	-0.0068	-0.0023	0	0.0038974
50	1.498e-13	1.5126e-13	1.564e-13	2.8841e-15	1.439e-13	1.4876e-13	1.502e-13	2.7208e-15	-0.0066	-0.0025	0.0004	0.0036993
60	1.496e-13	1.5244e-13	1.568e-13	3.8449e-15	1.501e-13	1.529e-13	1.574e-13	3.7967e-15	0.0002	0.00046	0.0006	0.00015166
100	1.499e-13	1.5416e-13	1.575e-13	3.8578e-15	1.5e-13	1.5164e-13	1.569e-13	2.9552e-15	-0.0067	-0.00252	0.0003	0.0037712
110	1.499e-13	1.5282e-13	1.569e-13	3.5954e-15	1.509e-13	1.5362e-13	1.578e-13	3.5081e-15	-0.006	0.0008	0.0079	0.0049178

Device Test: 56.1 V_CHANNEL_ON(EnSeq|PowerUp/VS1_to_COMP2/7/7///90.9/634//1.8//12/@V_CHANNEL_ON)





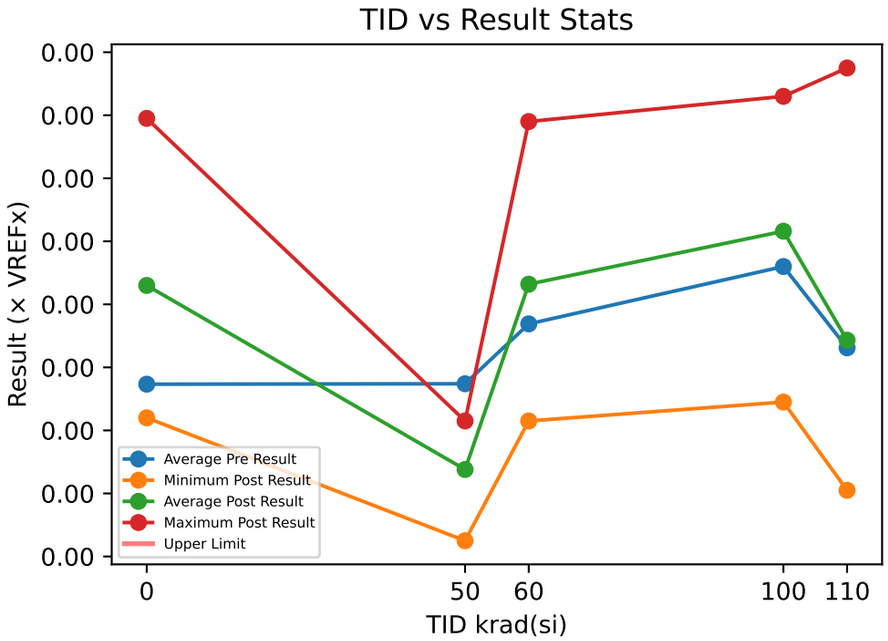
Test Results (No Limits Specified (× VREFx))

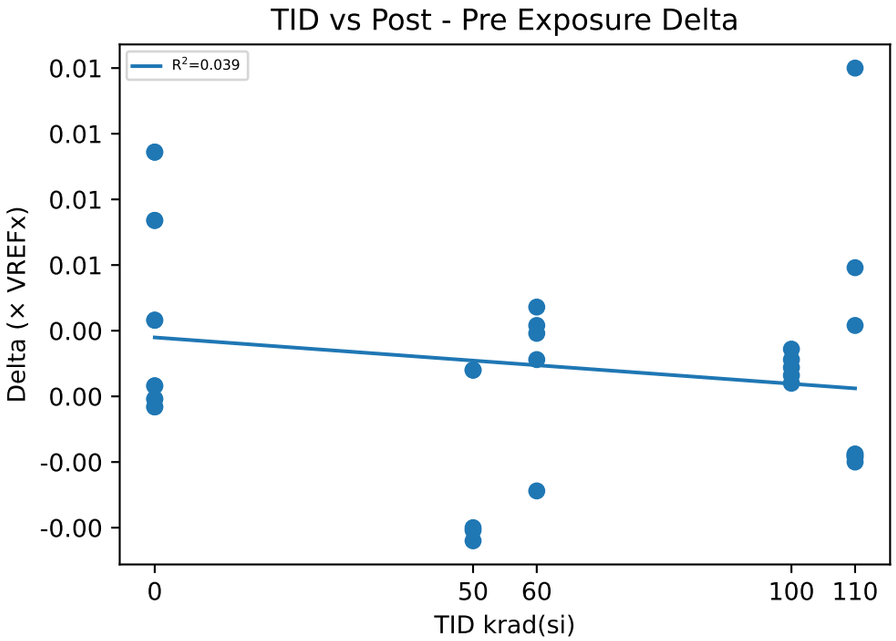
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.572e-13	8.571e-13	-0.0001
2	0	CU2	8.614e-13	8.613e-13	-0.0001
3	0	CU3	8.582e-13	8.578e-13	-0.0004
11	50	Unbiased-50k	8.603e-13	8.62e-13	0.0017
12	50	Unbiased-50k	8.563e-13	8.514e-13	-0.0049
13	50	Unbiased-50k	8.574e-13	8.584e-13	0.001
14	50	Unbiased-50k	8.585e-13	8.595e-13	0.001
16	50	Unbiased-50k	8.517e-13	8.529e-13	0.0012
17	60	Biased-50k	8.57e-13	8.525e-13	-0.0045
18	60	Biased-50k	8.601e-13	8.567e-13	-0.0034
19	60	Biased-50k	8.575e-13	8.535e-13	-0.004
20	60	Biased-50k	8.573e-13	8.538e-13	-0.0035
21	60	Biased-50k	8.556e-13	8.502e-13	-0.0054
24	100	Unbiased-100k	8.583e-13	8.598e-13	0.0015
25	100	Unbiased-100k	8.573e-13	8.584e-13	0.0011
26	100	Unbiased-100k	8.553e-13	8.571e-13	0.0018
27	100	Unbiased-100k	8.525e-13	8.53e-13	0.0005
28	100	Unbiased-100k	8.504e-13	8.512e-13	0.0008
29	110	Biased-100k	8.58e-13	8.625e-13	0.0045
30	110	Biased-100k	8.502e-13	8.529e-13	0.0027
31	110	Biased-100k	8.533e-13	8.58e-13	0.0047
32	110	Biased-100k	8.502e-13	8.552e-13	0.005
34	110	Biased-100k	8.537e-13	8.582e-13	0.0045

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.572e-13	8.5893e-13	8.614e-13	2.1939e-15	8.571e-13	8.5873e-13	8.613e-13	2.2502e-15	-0.0004	-0.0002	-0.0001	0.00017321
50	8.517e-13	8.5684e-13	8.603e-13	3.2308e-15	8.514e-13	8.5684e-13	8.62e-13	4.507e-15	-0.0049	2.2204e-17	0.0017	0.0027541
60	8.556e-13	8.575e-13	8.601e-13	1.6325e-15	8.502e-13	8.5334e-13	8.567e-13	2.3501e-15	-0.0054	-0.00416	-0.0034	0.00082037
100	8.504e-13	8.5476e-13	8.583e-13	3.2936e-15	8.512e-13	8.559e-13	8.598e-13	3.6538e-15	0.0005	0.00114	0.0018	0.00052249
110	8.502e-13	8.5308e-13	8.58e-13	3.2105e-15	8.529e-13	8.5736e-13	8.625e-13	3.6087e-15	0.0027	0.00428	0.005	0.00090664

Device Test: 56.2 V_CHANNEL_ON(EnSeq|PowerUp/VS2_to_COMP3/7/7///90.9/634//1.8//12/@V_CHANNEL_ON)





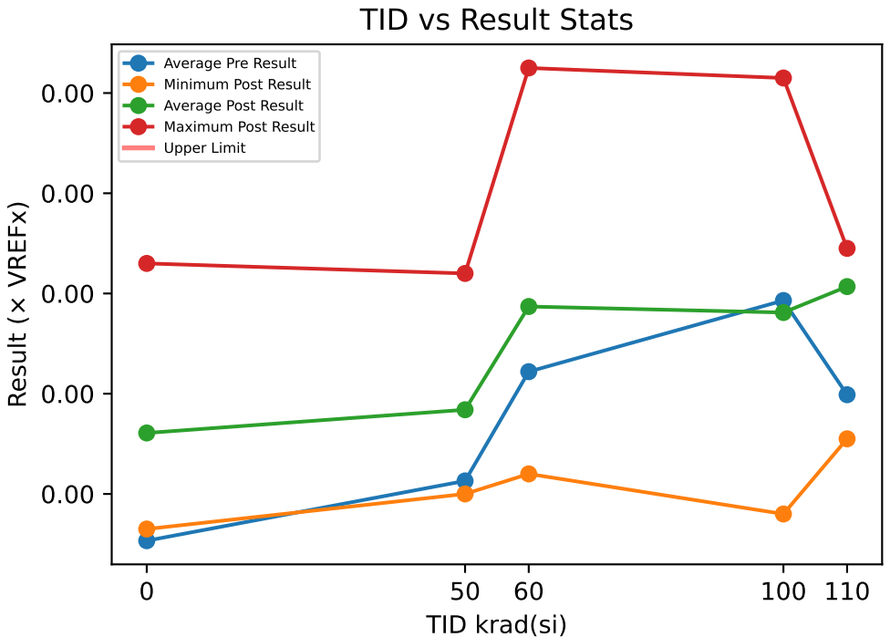
Test Results (No Limits Specified (× VREFx))

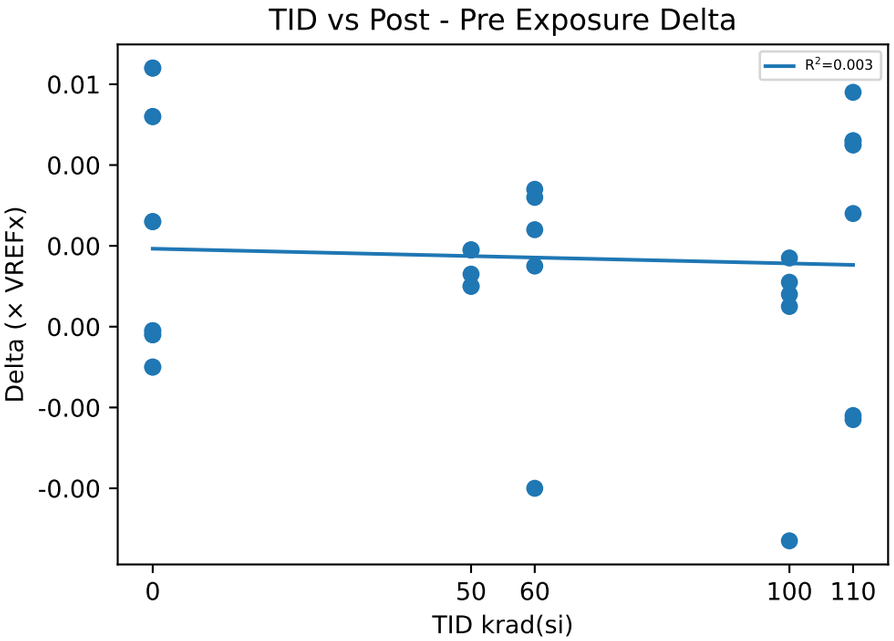
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.526e-13	8.525e-13	-0.0001
2	0	CU2	8.52e-13	8.587e-13	0.0067
3	0	CU3	8.558e-13	8.554e-13	-0.0004
11	50	Unbiased-50k	8.536e-13	8.485e-13	-0.0051
12	50	Unbiased-50k	8.573e-13	8.523e-13	-0.005
13	50	Unbiased-50k	8.5e-13	8.51e-13	0.001
14	50	Unbiased-50k	8.506e-13	8.516e-13	0.001
16	50	Unbiased-50k	8.559e-13	8.504e-13	-0.0055
17	60	Biased-50k	8.562e-13	8.586e-13	0.0024
18	60	Biased-50k	8.584e-13	8.618e-13	0.0034
19	60	Biased-50k	8.501e-13	8.528e-13	0.0027
20	60	Biased-50k	8.559e-13	8.523e-13	-0.0036
21	60	Biased-50k	8.563e-13	8.577e-13	0.0014
24	100	Unbiased-100k	8.515e-13	8.529e-13	0.0014
25	100	Unbiased-100k	8.57e-13	8.581e-13	0.0011
26	100	Unbiased-100k	8.576e-13	8.594e-13	0.0018
27	100	Unbiased-100k	8.621e-13	8.626e-13	0.0005
28	100	Unbiased-100k	8.578e-13	8.586e-13	0.0008
29	110	Biased-100k	8.588e-13	8.563e-13	-0.0025
30	110	Biased-100k	8.569e-13	8.596e-13	0.0027
31	110	Biased-100k	8.54e-13	8.589e-13	0.0049
32	110	Biased-100k	8.51e-13	8.635e-13	0.0125
34	110	Biased-100k	8.524e-13	8.501e-13	-0.0023

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.52e-13	8.5347e-13	8.558e-13	2.0429e-15	8.525e-13	8.5553e-13	8.587e-13	3.1021e-15	-0.0004	0.0020667	0.0067	0.0040154
50	8.5e-13	8.5348e-13	8.573e-13	3.1964e-15	8.485e-13	8.5076e-13	8.523e-13	1.4467e-15	-0.0055	-0.00272	0.001	0.003401
60	8.501e-13	8.5538e-13	8.584e-13	3.114e-15	8.523e-13	8.5664e-13	8.618e-13	4.0365e-15	-0.0036	0.00126	0.0034	0.0028103
100	8.515e-13	8.572e-13	8.621e-13	3.7769e-15	8.529e-13	8.5832e-13	8.626e-13	3.4996e-15	0.0005	0.00112	0.0018	0.00050695
110	8.51e-13	8.5462e-13	8.588e-13	3.205e-15	8.501e-13	8.5768e-13	8.635e-13	4.96e-15	-0.0025	0.00306	0.0125	0.0061699

Device Test: 56.3 V_CHANNEL_ON(EnSeq|PowerUp/VS3_to_COMP4/7/7///90.9/634//1.8//12/@V_CHANNEL_ON)





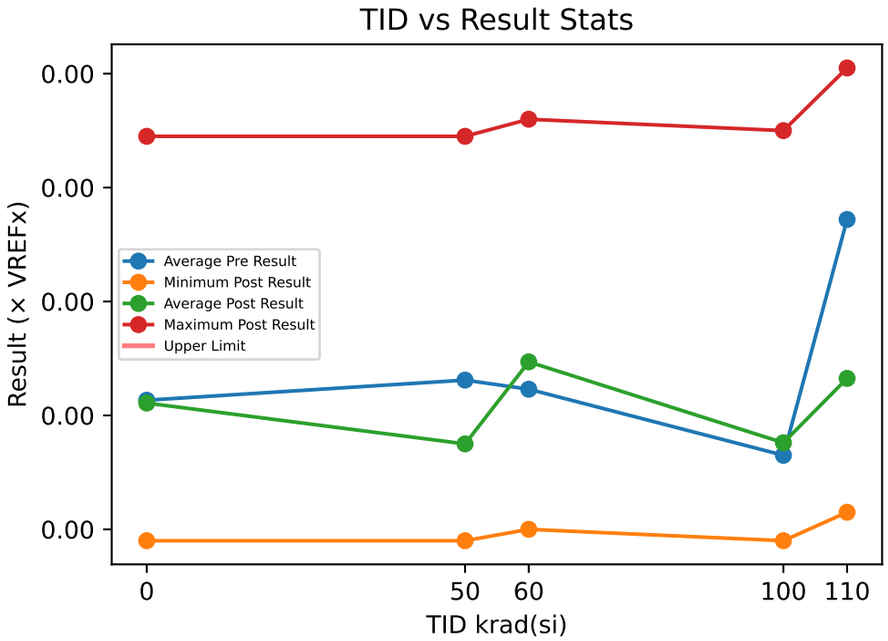
Test Results (No Limits Specified (× VREFx))

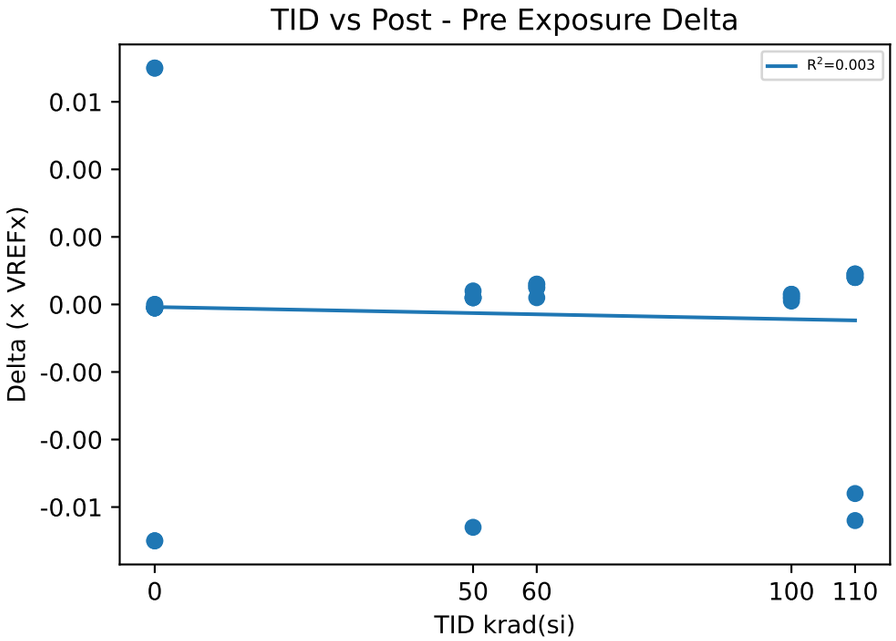
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.514e-13	8.513e-13	-0.0001
2	0	CU2	8.523e-13	8.521e-13	-0.0002
3	0	CU3	8.495e-13	8.559e-13	0.0064
11	50	Unbiased-50k	8.529e-13	8.548e-13	0.0019
12	50	Unbiased-50k	8.51e-13	8.529e-13	0.0019
13	50	Unbiased-50k	8.554e-13	8.564e-13	0.001
14	50	Unbiased-50k	8.51e-13	8.52e-13	0.001
16	50	Unbiased-50k	8.51e-13	8.523e-13	0.0013
17	60	Biased-50k	8.581e-13	8.605e-13	0.0024
18	60	Biased-50k	8.505e-13	8.539e-13	0.0034
19	60	Biased-50k	8.564e-13	8.524e-13	-0.004
20	60	Biased-50k	8.504e-13	8.536e-13	0.0032
21	60	Biased-50k	8.568e-13	8.583e-13	0.0015
24	100	Unbiased-100k	8.576e-13	8.523e-13	-0.0053
25	100	Unbiased-100k	8.592e-13	8.603e-13	0.0011
26	100	Unbiased-100k	8.499e-13	8.516e-13	0.0017
27	100	Unbiased-100k	8.536e-13	8.541e-13	0.0005
28	100	Unbiased-100k	8.59e-13	8.598e-13	0.0008
29	110	Biased-100k	8.583e-13	8.56e-13	-0.0023
30	110	Biased-100k	8.503e-13	8.531e-13	0.0028
31	110	Biased-100k	8.586e-13	8.564e-13	-0.0022
32	110	Biased-100k	8.504e-13	8.562e-13	0.0058
34	110	Biased-100k	8.523e-13	8.568e-13	0.0045

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.495e-13	8.5107e-13	8.523e-13	1.4295e-15	8.513e-13	8.531e-13	8.559e-13	2.4576e-15	-0.0002	0.0020333	0.0064	0.003782
50	8.51e-13	8.5226e-13	8.554e-13	1.9386e-15	8.52e-13	8.5368e-13	8.564e-13	1.87e-15	0.001	0.00142	0.0019	0.00045497
60	8.504e-13	8.5444e-13	8.581e-13	3.6963e-15	8.524e-13	8.5574e-13	8.605e-13	3.4761e-15	-0.004	0.0013	0.0034	0.0030561
100	8.499e-13	8.5586e-13	8.592e-13	4.0209e-15	8.516e-13	8.5562e-13	8.603e-13	4.1493e-15	-0.0053	-0.00024	0.0017	0.0028632
110	8.503e-13	8.5398e-13	8.586e-13	4.159e-15	8.531e-13	8.557e-13	8.568e-13	1.4832e-15	-0.0023	0.00172	0.0058	0.0037772

Device Test: 56.4 V_CHANNEL_OFF(EnSeq|PowerDown/VS4_to_COMP3/7/7///90.9/634//1.8//12/@V_CHANNEL_OFF)





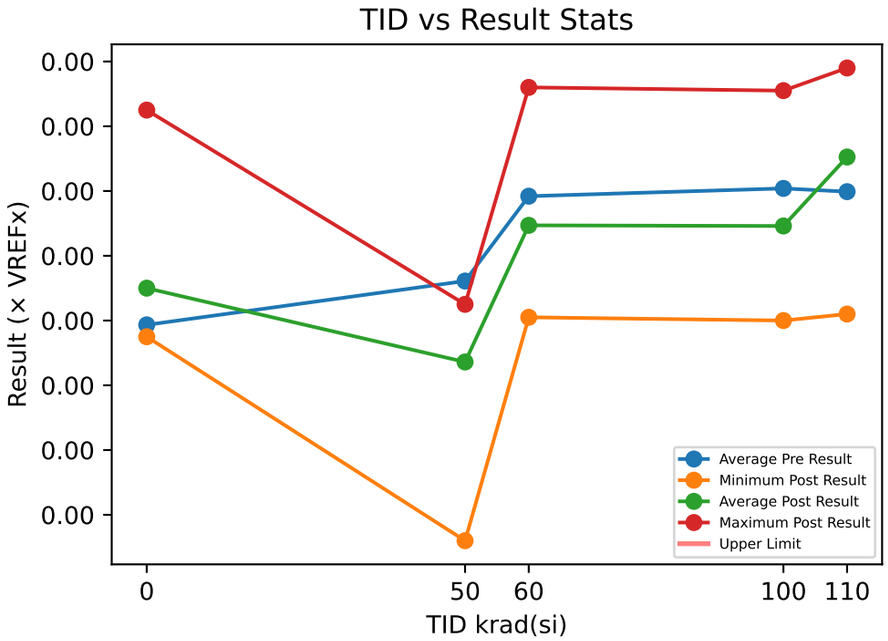
Test Results (No Limits Specified (× VREFx))

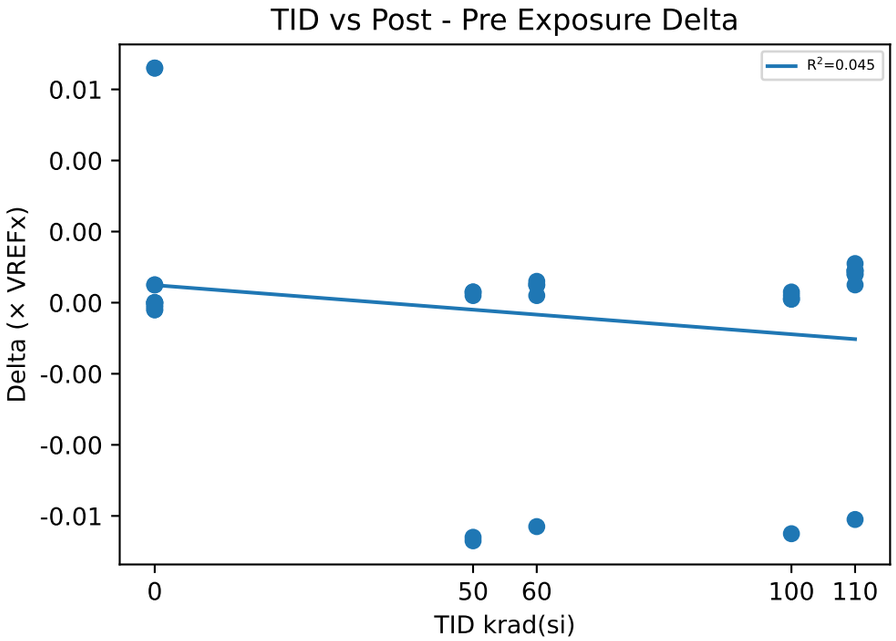
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.5e-13	1.499e-13	-0.0001
2	0	CU2	1.569e-13	1.569e-13	0
3	0	CU3	1.499e-13	1.498e-13	-0.0001
11	50	Unbiased-50k	1.571e-13	1.505e-13	-0.0066
12	50	Unbiased-50k	1.565e-13	1.569e-13	0.0004
13	50	Unbiased-50k	1.496e-13	1.498e-13	0.0002
14	50	Unbiased-50k	1.5e-13	1.502e-13	0.0002
16	50	Unbiased-50k	1.499e-13	1.501e-13	0.0002
17	60	Biased-50k	1.496e-13	1.501e-13	0.0005
18	60	Biased-50k	1.498e-13	1.504e-13	0.0006
19	60	Biased-50k	1.565e-13	1.57e-13	0.0005
20	60	Biased-50k	1.566e-13	1.572e-13	0.0006
21	60	Biased-50k	1.498e-13	1.5e-13	0.0002
24	100	Unbiased-100k	1.5e-13	1.503e-13	0.0003
25	100	Unbiased-100k	1.496e-13	1.498e-13	0.0002
26	100	Unbiased-100k	1.498e-13	1.501e-13	0.0003
27	100	Unbiased-100k	1.503e-13	1.504e-13	0.0001
28	100	Unbiased-100k	1.568e-13	1.57e-13	0.0002
29	110	Biased-100k	1.567e-13	1.575e-13	0.0008
30	110	Biased-100k	1.567e-13	1.503e-13	-0.0064
31	110	Biased-100k	1.572e-13	1.581e-13	0.0009
32	110	Biased-100k	1.563e-13	1.507e-13	-0.0056
34	110	Biased-100k	1.503e-13	1.511e-13	0.0008

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.499e-13	1.5227e-13	1.569e-13	4.0129e-15	1.498e-13	1.522e-13	1.569e-13	4.0706e-15	-0.0001	-6.6667e-05	0	5.7735e-05
50	1.496e-13	1.5262e-13	1.571e-13	3.8245e-15	1.498e-13	1.515e-13	1.569e-13	3.029e-15	-0.0066	-0.00112	0.0004	0.0030646
60	1.496e-13	1.5246e-13	1.566e-13	3.7347e-15	1.5e-13	1.5294e-13	1.572e-13	3.8011e-15	0.0002	0.00048	0.0006	0.00016432
100	1.496e-13	1.513e-13	1.568e-13	3.0854e-15	1.498e-13	1.5152e-13	1.57e-13	3.072e-15	0.0001	0.00022	0.0003	8.3666e-05
110	1.503e-13	1.5544e-13	1.572e-13	2.891e-15	1.503e-13	1.5354e-13	1.581e-13	3.9049e-15	-0.0064	-0.0019	0.0009	0.0037537

Device Test: 56.5 V_CHANNEL_OFF(EnSeq|PowerDown/VS3_to_COMP2/7/7///90.9/634//1.8//12/@V_CHANNEL_OFF)





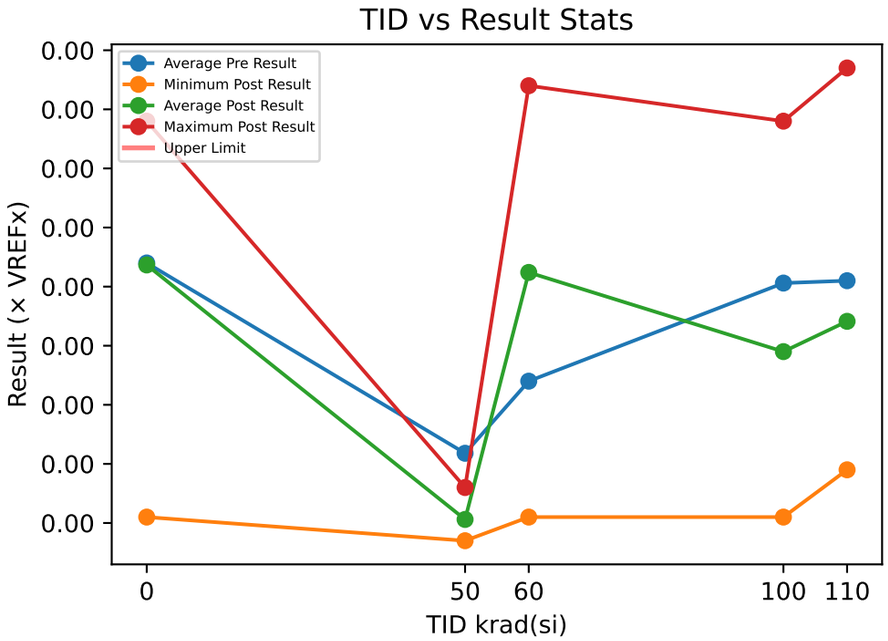
Test Results (No Limits Specified (× VREFx))

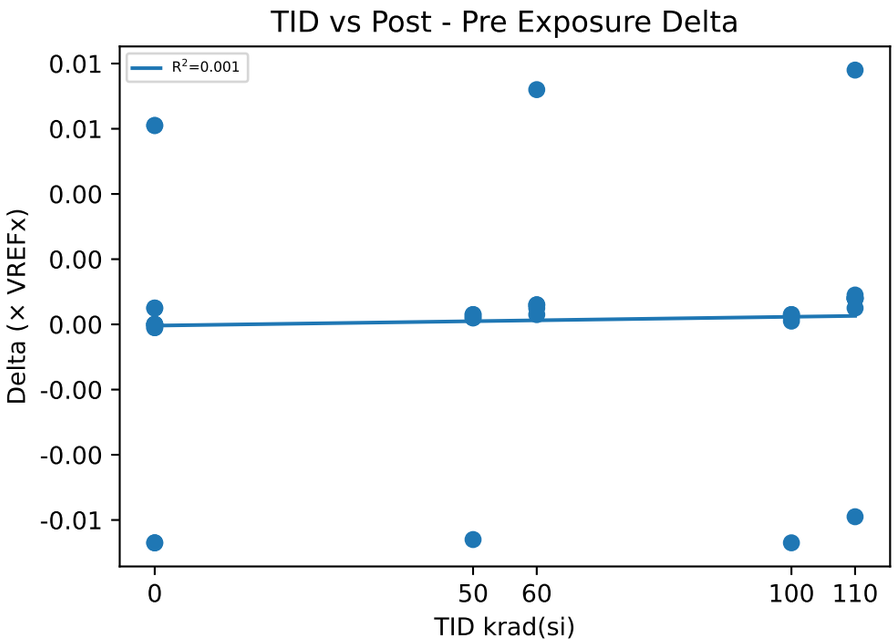
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.499e-13	1.499e-13	0
2	0	CU2	1.501e-13	1.501e-13	0
3	0	CU3	1.496e-13	1.495e-13	-0.0001
11	50	Unbiased-50k	1.502e-13	1.505e-13	0.0003
12	50	Unbiased-50k	1.499e-13	1.502e-13	0.0003
13	50	Unbiased-50k	1.562e-13	1.496e-13	-0.0066
14	50	Unbiased-50k	1.499e-13	1.432e-13	-0.0067
16	50	Unbiased-50k	1.499e-13	1.501e-13	0.0002
17	60	Biased-50k	1.567e-13	1.572e-13	0.0005
18	60	Biased-50k	1.498e-13	1.504e-13	0.0006
19	60	Biased-50k	1.564e-13	1.501e-13	-0.0063
20	60	Biased-50k	1.498e-13	1.503e-13	0.0005
21	60	Biased-50k	1.565e-13	1.567e-13	0.0002
24	100	Unbiased-100k	1.566e-13	1.501e-13	-0.0065
25	100	Unbiased-100k	1.569e-13	1.571e-13	0.0002
26	100	Unbiased-100k	1.497e-13	1.5e-13	0.0003
27	100	Unbiased-100k	1.503e-13	1.504e-13	0.0001
28	100	Unbiased-100k	1.569e-13	1.57e-13	0.0001
29	110	Biased-100k	1.568e-13	1.507e-13	-0.0061
30	110	Biased-100k	1.497e-13	1.502e-13	0.0005
31	110	Biased-100k	1.568e-13	1.577e-13	0.0009
32	110	Biased-100k	1.497e-13	1.508e-13	0.0011
34	110	Biased-100k	1.569e-13	1.577e-13	0.0008

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.496e-13	1.4987e-13	1.501e-13	2.5166e-16	1.495e-13	1.4983e-13	1.501e-13	3.0551e-16	-0.0001	-3.3333e-05	0	5.7735e-05
50	1.499e-13	1.5122e-13	1.562e-13	2.7869e-15	1.432e-13	1.4872e-13	1.505e-13	3.1027e-15	-0.0067	-0.0025	0.0003	0.0037888
60	1.498e-13	1.5384e-13	1.567e-13	3.6896e-15	1.501e-13	1.5294e-13	1.572e-13	3.6665e-15	-0.0063	-0.0009	0.0006	0.0030224
100	1.497e-13	1.5408e-13	1.569e-13	3.7326e-15	1.5e-13	1.5292e-13	1.571e-13	3.7732e-15	-0.0065	-0.00116	0.0003	0.0029863
110	1.497e-13	1.5398e-13	1.569e-13	3.9073e-15	1.502e-13	1.5342e-13	1.577e-13	3.9137e-15	-0.0061	-0.00056	0.0011	0.0031045

Device Test: 56.6 V_CHANNEL_OFF(EnSeq|PowerDown/VS2_to_COMP1/7/7///90.9/634//1.8//12/@V_CHANNEL_OFF)





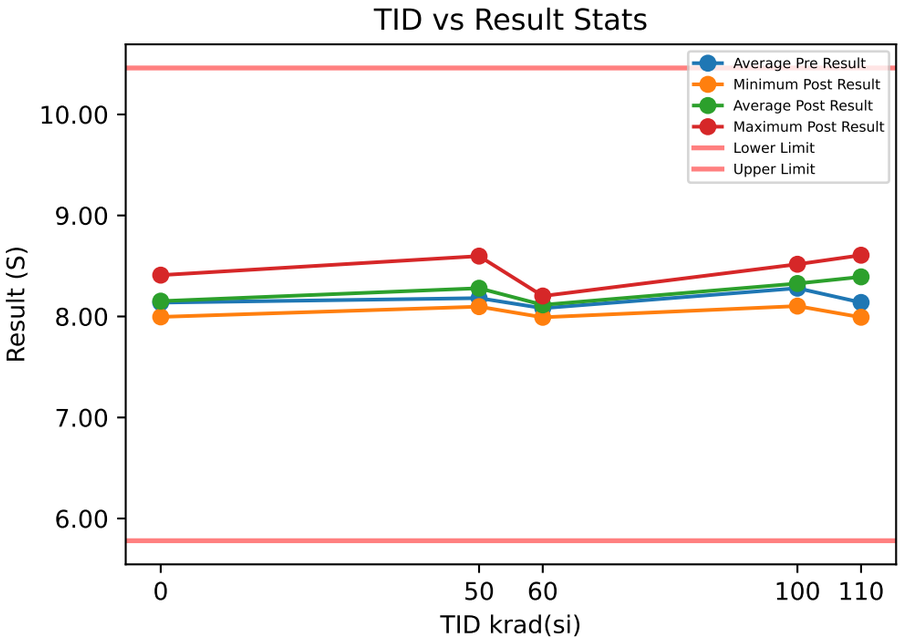
Test Results (No Limits Specified (× VREFx))

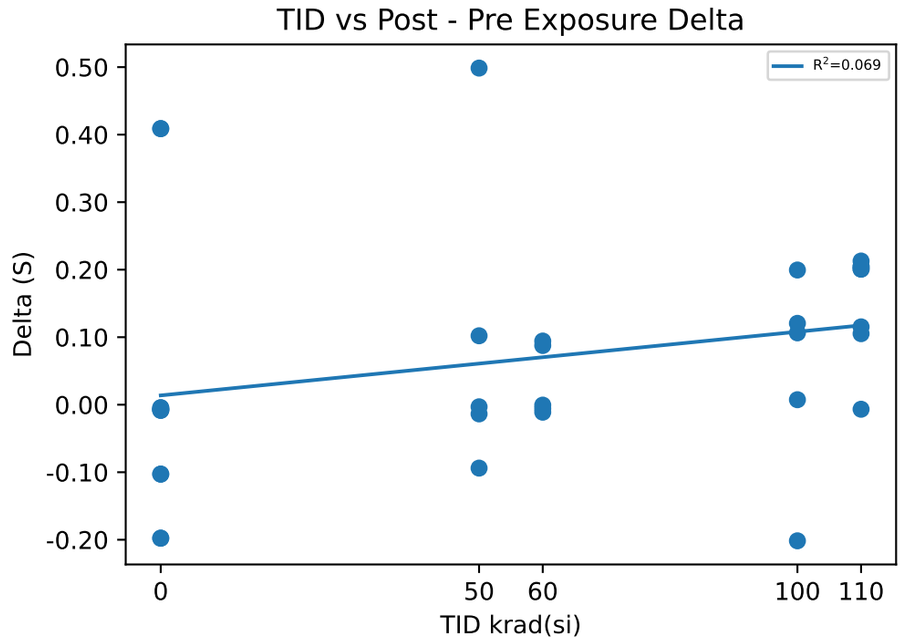
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.501e-13	1.501e-13	0
2	0	CU2	1.568e-13	1.568e-13	0
3	0	CU3	1.563e-13	1.562e-13	-0.0001
11	50	Unbiased-50k	1.503e-13	1.506e-13	0.0003
12	50	Unbiased-50k	1.498e-13	1.501e-13	0.0003
13	50	Unbiased-50k	1.497e-13	1.499e-13	0.0002
14	50	Unbiased-50k	1.498e-13	1.5e-13	0.0002
16	50	Unbiased-50k	1.563e-13	1.497e-13	-0.0066
17	60	Biased-50k	1.496e-13	1.568e-13	0.0072
18	60	Biased-50k	1.568e-13	1.574e-13	0.0006
19	60	Biased-50k	1.497e-13	1.502e-13	0.0005
20	60	Biased-50k	1.495e-13	1.501e-13	0.0006
21	60	Biased-50k	1.564e-13	1.567e-13	0.0003
24	100	Unbiased-100k	1.499e-13	1.502e-13	0.0003
25	100	Unbiased-100k	1.565e-13	1.567e-13	0.0002
26	100	Unbiased-100k	1.498e-13	1.501e-13	0.0003
27	100	Unbiased-100k	1.574e-13	1.507e-13	-0.0067
28	100	Unbiased-100k	1.567e-13	1.568e-13	0.0001
29	110	Biased-100k	1.568e-13	1.577e-13	0.0009
30	110	Biased-100k	1.565e-13	1.57e-13	0.0005
31	110	Biased-100k	1.572e-13	1.513e-13	-0.0059
32	110	Biased-100k	1.499e-13	1.577e-13	0.0078
34	110	Biased-100k	1.501e-13	1.509e-13	0.0008

Test Statistics (× VREFx)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.501e-13	1.544e-13	1.568e-13	3.7323e-15	1.501e-13	1.5437e-13	1.568e-13	3.7072e-15	-0.0001	-3.3333e-05	0	5.7735e-05
50	1.497e-13	1.5118e-13	1.563e-13	2.8718e-15	1.497e-13	1.5006e-13	1.506e-13	3.3615e-16	-0.0066	-0.00112	0.0003	0.0030638
60	1.495e-13	1.524e-13	1.568e-13	3.8373e-15	1.501e-13	1.5424e-13	1.574e-13	3.7434e-15	0.0003	0.00184	0.0072	0.0029988
100	1.498e-13	1.5406e-13	1.574e-13	3.8578e-15	1.501e-13	1.529e-13	1.568e-13	3.5221e-15	-0.0067	-0.00116	0.0003	0.0030981
110	1.499e-13	1.541e-13	1.572e-13	3.7517e-15	1.509e-13	1.5492e-13	1.577e-13	3.5017e-15	-0.0059	0.00082	0.0078	0.0048474

Device Test: 68.17 PS_GM(EA_GMPS|GMPS/CH1/3/3///90.9/634//0///@PS_GM)





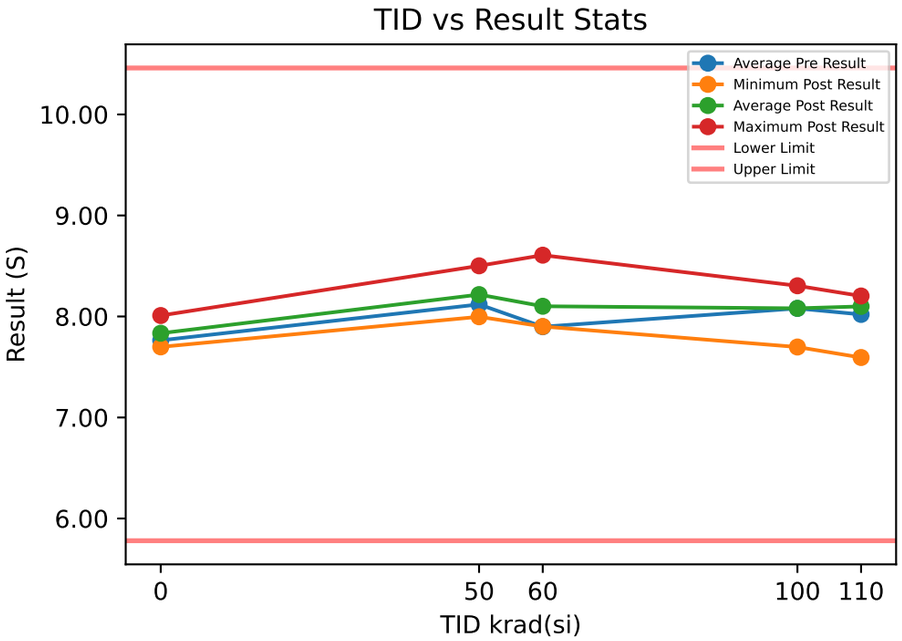
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

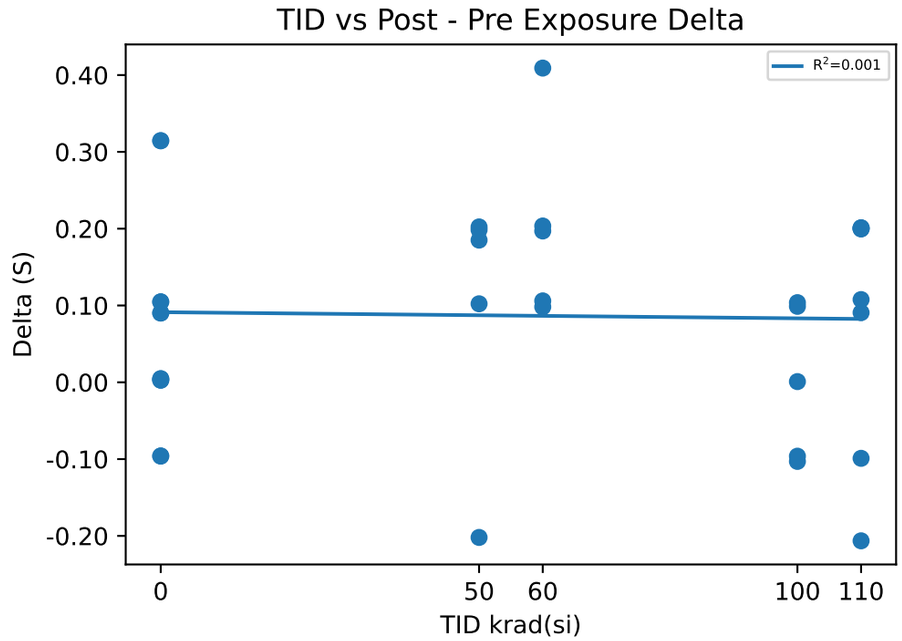
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.0002	7.9957	-0.0045
2	0	CU2	8.1095	8.1024	-0.0071
3	0	CU3	8.3017	8.2934	-0.0083
11	50	Unbiased-50k	7.995	8.0971	0.1021
12	50	Unbiased-50k	8.2095	8.1959	-0.0136
13	50	Unbiased-50k	8.3109	8.3078	-0.0031
14	50	Unbiased-50k	8.099	8.5976	0.4986
16	50	Unbiased-50k	8.2938	8.1999	-0.0939
17	60	Biased-50k	8.099	8.0984	-0.0006
18	60	Biased-50k	8.0029	7.9918	-0.0111
19	60	Biased-50k	8.1082	8.2025	0.0943
20	60	Biased-50k	8.1977	8.192	-0.0057
21	60	Biased-50k	8.0015	8.0892	0.0877
24	100	Unbiased-100k	7.9989	8.1053	0.1064
25	100	Unbiased-100k	8.3043	8.1027	-0.2016
26	100	Unbiased-100k	8.3965	8.517	0.1205
27	100	Unbiased-100k	8.3017	8.5012	0.1995
28	100	Unbiased-100k	8.3978	8.4052	0.0074
29	110	Biased-100k	8.1016	8.3144	0.2128
30	110	Biased-100k	7.8975	8.0027	0.1052
31	110	Biased-100k	7.9989	7.9922	-0.0067
32	110	Biased-100k	8.2938	8.4091	0.1153
34	110	Biased-100k	8.4017	8.6064	0.2047

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0002	8.1371	8.3017	0.15264	7.9957	8.1305	8.2934	0.15083	-0.0083	-0.0066333	-0.0045	0.0019425
50	7.995	8.1816	8.3109	0.13391	8.0971	8.2797	8.5976	0.19273	-0.0939	0.09802	0.4986	0.23452
60	8.0015	8.0819	8.1977	0.082309	7.9918	8.1148	8.2025	0.086175	-0.0111	0.03292	0.0943	0.053201
100	7.9989	8.2798	8.3978	0.16396	8.1027	8.3263	8.517	0.20738	-0.2016	0.04644	0.1995	0.15456
110	7.8975	8.1387	8.4017	0.20756	7.9922	8.265	8.6064	0.26598	-0.0067	0.12626	0.2128	0.08928

Device Test: 68.18 PS_GM(EA_GMPS|GMPS/CH2/3/3///90.9/634//0///@PS_GM)





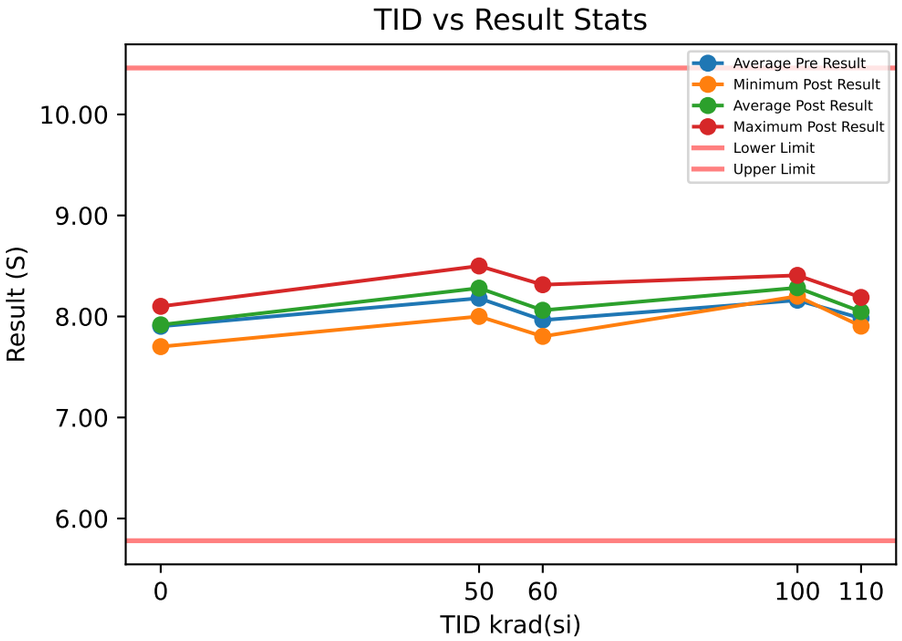
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

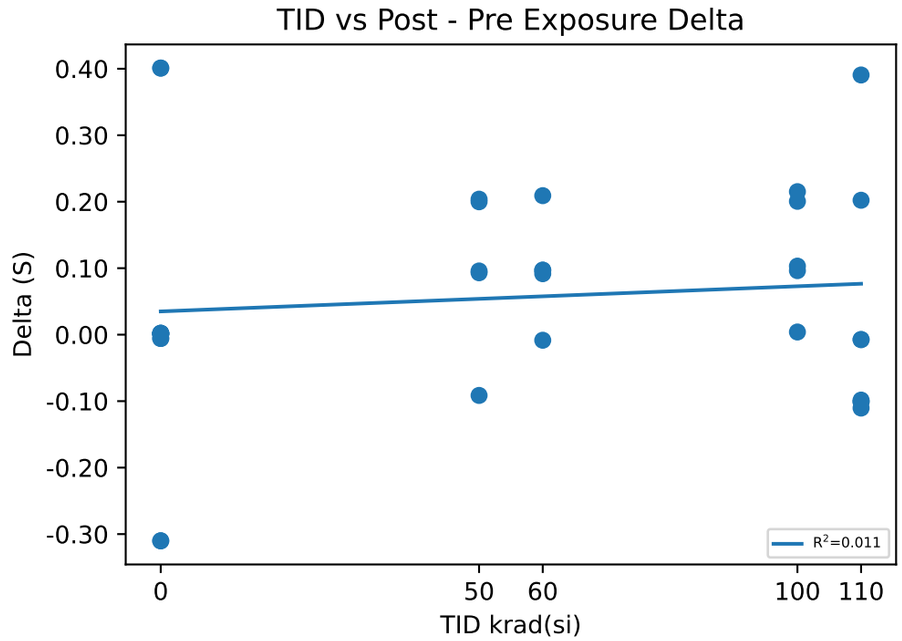
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	7.6948	7.6994	0.0046
2	0	CU2	7.6961	7.8008	0.1047
3	0	CU3	7.9002	7.9904	0.0902
11	50	Unbiased-50k	8.303	8.5015	0.1985
12	50	Unbiased-50k	8.199	7.997	-0.202
13	50	Unbiased-50k	8.0029	8.188	0.1851
14	50	Unbiased-50k	8.1951	8.2973	0.1022
16	50	Unbiased-50k	7.8975	8.0998	0.2023
17	60	Biased-50k	7.6974	7.9009	0.2035
18	60	Biased-50k	7.995	8.192	0.197
19	60	Biased-50k	8.1977	8.6068	0.4091
20	60	Biased-50k	7.8027	7.9009	0.0982
21	60	Biased-50k	7.7988	7.9048	0.106
24	100	Unbiased-100k	8.0976	8.0014	-0.0962
25	100	Unbiased-100k	8.3017	8.1987	-0.103
26	100	Unbiased-100k	8.303	8.3039	0.0009
27	100	Unbiased-100k	8.0976	8.2013	0.1037
28	100	Unbiased-100k	7.5987	7.6976	0.0989
29	110	Biased-100k	7.9989	8.1066	0.1077
30	110	Biased-100k	7.8001	7.5937	-0.2064
31	110	Biased-100k	8.0002	8.0909	0.0907
32	110	Biased-100k	8.3017	8.2027	-0.099
34	110	Biased-100k	8.0002	8.2	0.1998

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.6948	7.7637	7.9002	0.11821	7.6994	7.8302	7.9904	0.14771	0.0046	0.0665	0.1047	0.054095
50	7.8975	8.1195	8.303	0.16476	7.997	8.2167	8.5015	0.19388	-0.202	0.09722	0.2023	0.17218
60	7.6974	7.8983	8.1977	0.19899	7.9009	8.1011	8.6068	0.30931	0.0982	0.20276	0.4091	0.1254
100	7.5987	8.0797	8.303	0.28773	7.6976	8.0806	8.3039	0.24049	-0.103	0.00086	0.1037	0.10049
110	7.8001	8.0202	8.3017	0.17954	7.5937	8.0388	8.2027	0.2541	-0.2064	0.01856	0.1998	0.16615

Device Test: 68.19 PS_GM(EA_GMPS|GMPS/CH3/3/3///90.9/634//0///@PS_GM)





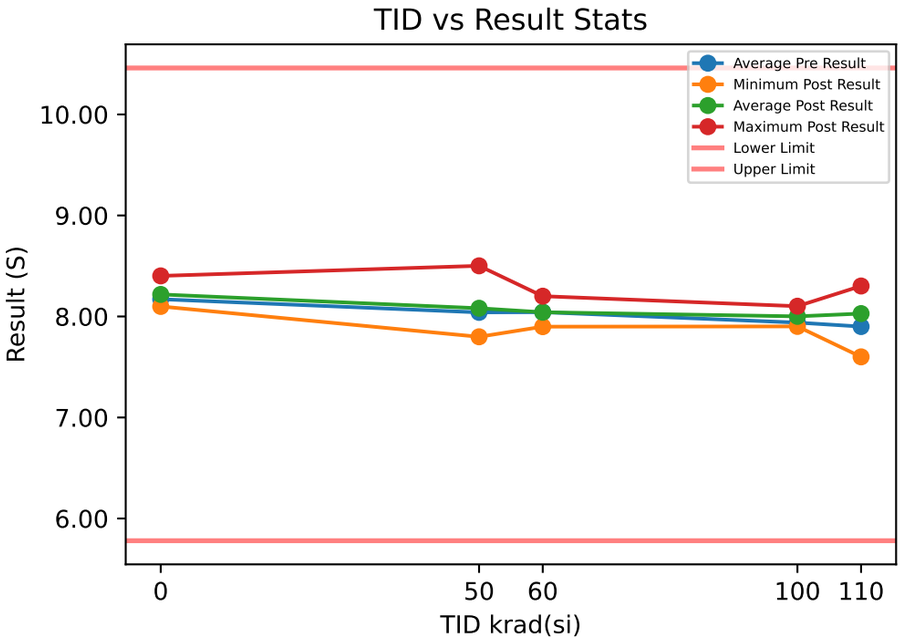
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

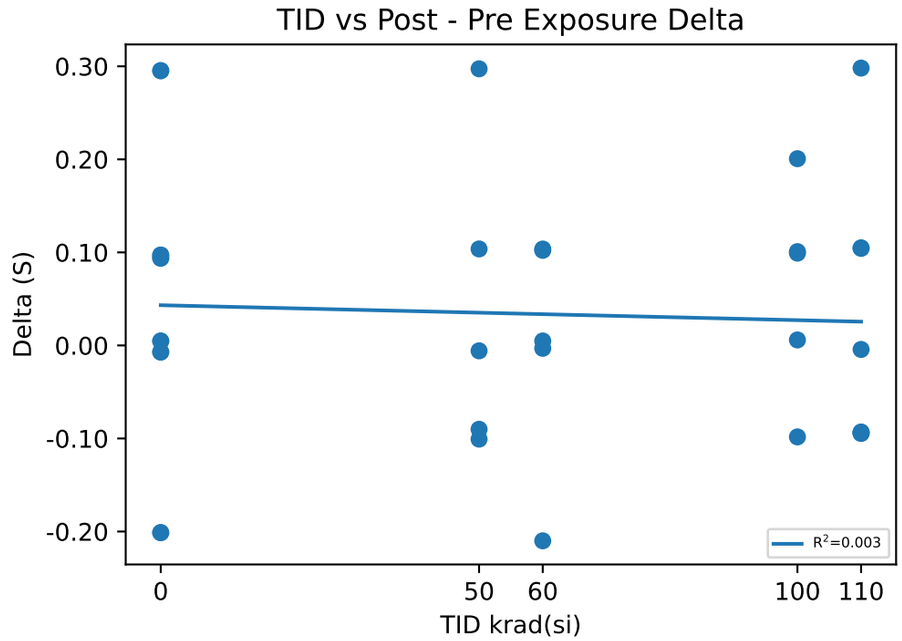
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	7.6992	7.7013	0.0021
2	0	CU2	8.0115	8.0058	-0.0057
3	0	CU3	7.997	7.9978	0.0008
11	50	Unbiased-50k	8.2026	8.2984	0.0958
12	50	Unbiased-50k	8.3001	8.5	0.1999
13	50	Unbiased-50k	8.2092	8.3023	0.0931
14	50	Unbiased-50k	8.0919	8.0005	-0.0914
16	50	Unbiased-50k	8.0985	8.3023	0.2038
17	60	Biased-50k	7.7058	7.8028	0.097
18	60	Biased-50k	8.001	8.098	0.097
19	60	Biased-50k	8.1051	8.3142	0.2091
20	60	Biased-50k	8.001	8.0927	0.0917
21	60	Biased-50k	8.0076	7.9992	-0.0084
24	100	Unbiased-100k	8.3054	8.4017	0.0963
25	100	Unbiased-100k	7.9997	8.2003	0.2006
26	100	Unbiased-100k	8.1011	8.2042	0.1031
27	100	Unbiased-100k	8.4029	8.4069	0.004
28	100	Unbiased-100k	7.9944	8.2095	0.2151
29	110	Biased-100k	8.2988	8.1884	-0.1104
30	110	Biased-100k	7.6083	7.9989	0.3906
31	110	Biased-100k	7.7019	7.9041	0.2022
32	110	Biased-100k	8.2013	8.1029	-0.0984
34	110	Biased-100k	8.1011	8.0937	-0.0074

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.6992	7.9026	8.0115	0.17627	7.7013	7.9016	8.0058	0.17354	-0.0057	-0.00093333	0.0021	0.0041789
50	8.0919	8.1805	8.3001	0.086877	8.0005	8.2807	8.5	0.17878	-0.0914	0.10024	0.2038	0.11985
60	7.7058	7.9641	8.1051	0.15101	7.8028	8.0614	8.3142	0.18505	-0.0084	0.09728	0.2091	0.076979
100	7.9944	8.1607	8.4029	0.18488	8.2003	8.2845	8.4069	0.10941	0.004	0.12382	0.2151	0.086271
110	7.6083	7.9823	8.2988	0.30852	7.9041	8.0576	8.1884	0.10894	-0.1104	0.07532	0.3906	0.21623

Device Test: 68.20 PS_GM(EA_GMPS|GMPS/CH4/3/3///90.9/634//0///@PS_GM)





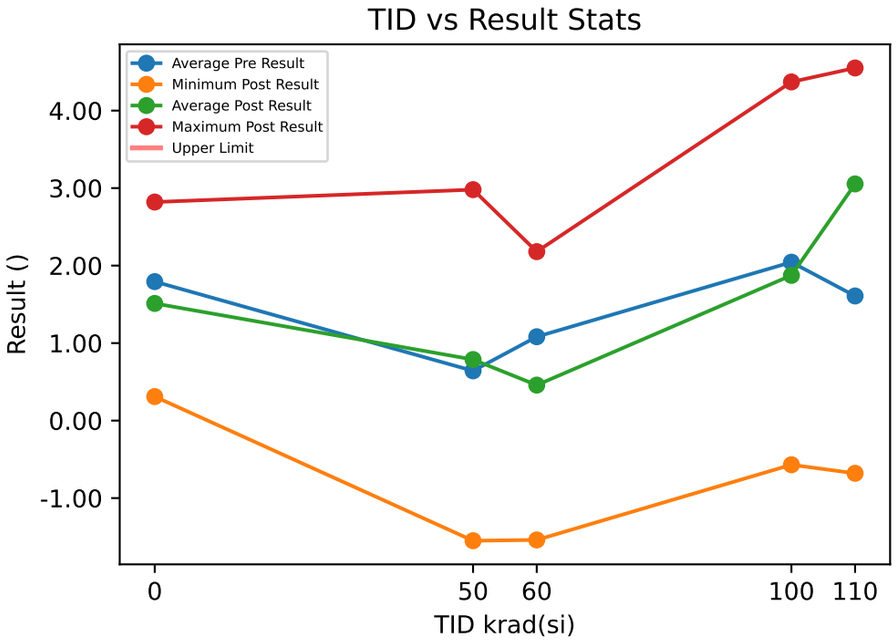
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

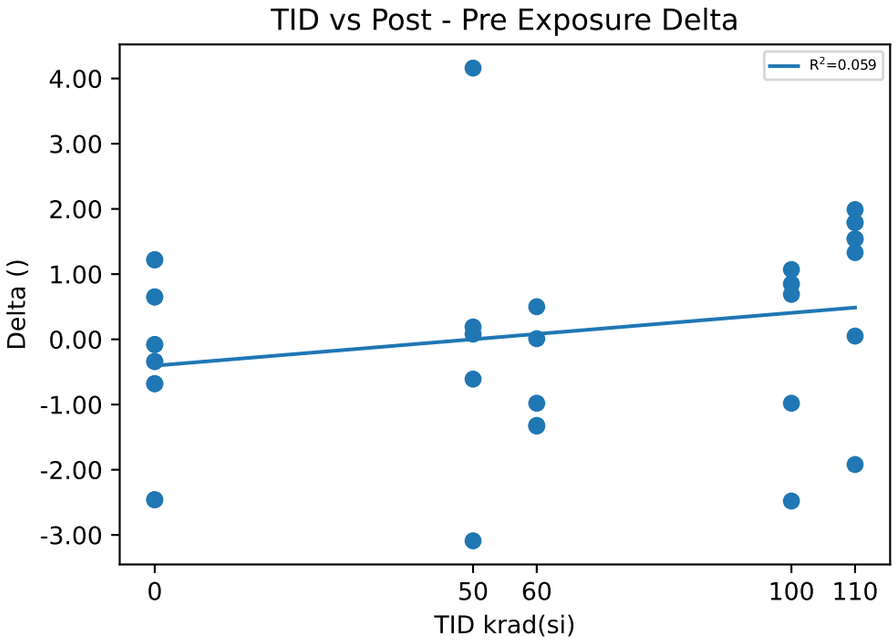
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.1025	8.1072	0.0047
2	0	CU2	8.3041	8.4012	0.0971
3	0	CU3	8.1064	8.0993	-0.0071
11	50	Unbiased-50k	8.0089	8.0031	-0.0058
12	50	Unbiased-50k	7.8995	7.7988	-0.1007
13	50	Unbiased-50k	8.1973	8.1072	-0.0901
14	50	Unbiased-50k	8.3976	8.5013	0.1037
16	50	Unbiased-50k	7.6992	7.9965	0.2973
17	60	Biased-50k	7.7994	7.9016	0.1022
18	60	Biased-50k	8.0023	8.1059	0.1036
19	60	Biased-50k	8.2039	8.2008	-0.0031
20	60	Biased-50k	8.109	7.899	-0.21
21	60	Biased-50k	8.0972	8.102	0.0048
24	100	Unbiased-100k	8.001	8.1002	0.0992
25	100	Unbiased-100k	7.8007	7.9015	0.1008
26	100	Unbiased-100k	8.0985	8.0002	-0.0983
27	100	Unbiased-100k	7.9009	8.1016	0.2007
28	100	Unbiased-100k	7.8956	7.9015	0.0059
29	110	Biased-100k	7.6044	7.6001	-0.0043
30	110	Biased-100k	7.5965	7.7014	0.1049
31	110	Biased-100k	7.9022	8.2003	0.2981
32	110	Biased-100k	8.1973	8.3016	0.1043
34	110	Biased-100k	8.2	8.1055	-0.0945

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.1025	8.171	8.3041	0.11528	8.0993	8.2026	8.4012	0.17207	-0.0071	0.031567	0.0971	0.057059
50	7.6992	8.0405	8.3976	0.26901	7.7988	8.0814	8.5013	0.2599	-0.1007	0.04088	0.2973	0.16513
60	7.7994	8.0424	8.2039	0.15344	7.899	8.0419	8.2008	0.13515	-0.21	-0.0005	0.1036	0.12778
100	7.8007	7.9393	8.0985	0.11374	7.9015	8.001	8.1016	0.099702	-0.0983	0.06166	0.2007	0.11288
110	7.5965	7.9001	8.2	0.29912	7.6001	7.9818	8.3016	0.3121	-0.0945	0.0817	0.2981	0.1469

Device Test: 68.21 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH1/3/3///90.9/634//0///@PS_GM_MATCH)





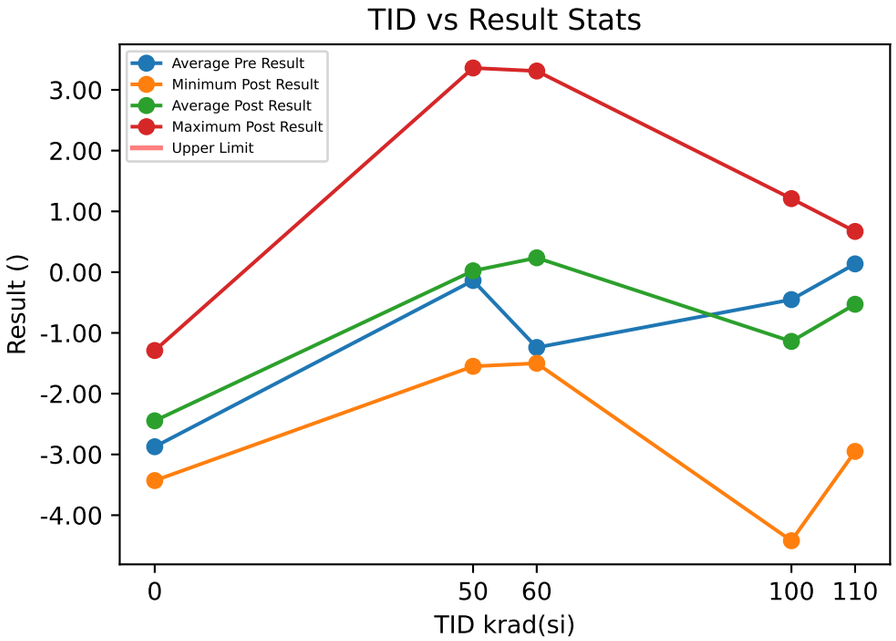
Test Results (No Limits Specified ())

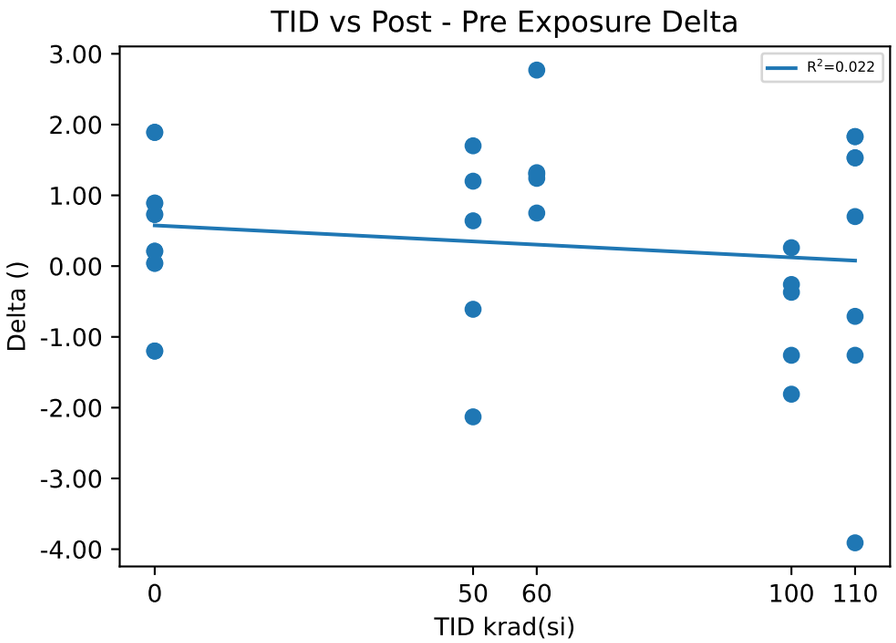
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.6	1.52	-0.08
2	0	CU2	0.99	0.31	-0.68
3	0	CU3	2.79	2.45	-0.34
11	50	Unbiased-50k	-1.63	-1.55	0.08
12	50	Unbiased-50k	0.71	0.9	0.19
13	50	Unbiased-50k	1.6	0.99	-0.61
14	50	Unbiased-50k	-1.18	2.98	4.16
16	50	Unbiased-50k	3.71	0.62	-3.09
17	60	Biased-50k	3.5	2.18	-1.32
18	60	Biased-50k	0.03	-1.3	-1.33
19	60	Biased-50k	-0.56	-1.54	-0.98
20	60	Biased-50k	2.12	2.13	0.01
21	60	Biased-50k	0.32	0.82	0.5
24	100	Unbiased-100k	-1.26	-0.57	0.69
25	100	Unbiased-100k	2.5	0.02	-2.48
26	100	Unbiased-100k	2.09	3.16	1.07
27	100	Unbiased-100k	1.54	2.39	0.85
28	100	Unbiased-100k	5.35	4.37	-0.98
29	110	Biased-100k	1.26	3.25	1.99
30	110	Biased-100k	2.23	2.28	0.05
31	110	Biased-100k	1.24	-0.68	-1.92
32	110	Biased-100k	0.55	1.88	1.33
34	110	Biased-100k	2.76	4.3	1.54

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.99	1.7933	2.79	0.91544	0.31	1.4267	2.45	1.073	-0.68	-0.36667	-0.08	0.30089
50	-1.63	0.642	3.71	2.1689	-1.55	0.788	2.98	1.6088	-3.09	0.146	4.16	2.6058
60	-0.56	1.082	3.5	1.6813	-1.54	0.458	2.18	1.801	-1.33	-0.624	0.5	0.8329
100	-1.26	2.044	5.35	2.3617	-0.57	1.874	4.37	2.0953	-2.48	-0.17	1.07	1.5256
110	0.55	1.608	2.76	0.8789	-0.68	2.206	4.3	1.8652	-1.92	0.598	1.99	1.5813

Device Test: 68.22 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH2/3/3///90.9/634//0///@PS_GM_MATCH)





Test Results (No Limits Specified ())

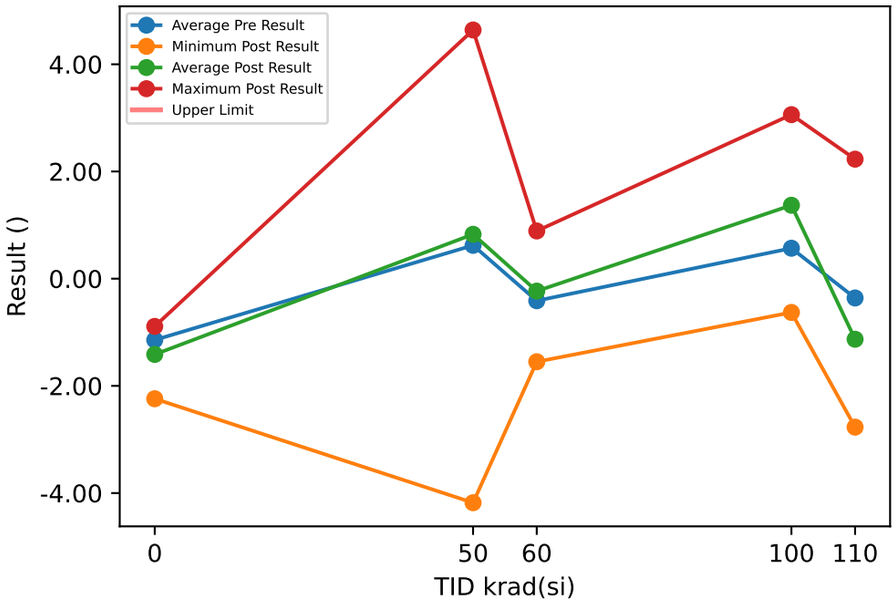
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-2.28	-2.24	0.04
2	0	CU2	-4.16	-3.43	0.73
3	0	CU3	-2.18	-1.29	0.89
11	50	Unbiased-50k	2.16	3.36	1.2
12	50	Unbiased-50k	0.58	-1.55	-2.13
13	50	Unbiased-50k	-2.17	-0.47	1.7
14	50	Unbiased-50k	-0.01	-0.62	-0.61
16	50	Unbiased-50k	-1.25	-0.61	0.64
17	60	Biased-50k	-1.64	-0.32	1.32
18	60	Biased-50k	-0.07	1.17	1.24
19	60	Biased-50k	0.54	3.31	2.77
20	60	Biased-50k	-2.8	-1.5	1.3
21	60	Biased-50k	-2.23	-1.48	0.75
24	100	Unbiased-100k	-0.04	-1.85	-1.81
25	100	Unbiased-100k	2.47	1.21	-1.26
26	100	Unbiased-100k	0.95	0.58	-0.37
27	100	Unbiased-100k	-0.96	-1.22	-0.26
28	100	Unbiased-100k	-4.68	-4.42	0.26
29	110	Biased-100k	-0.03	0.67	0.7
30	110	Biased-100k	0.96	-2.95	-3.91
31	110	Biased-100k	1.26	0.55	-0.71
32	110	Biased-100k	0.64	-0.62	-1.26
34	110	Biased-100k	-2.15	-0.62	1.53

Test Statistics ()

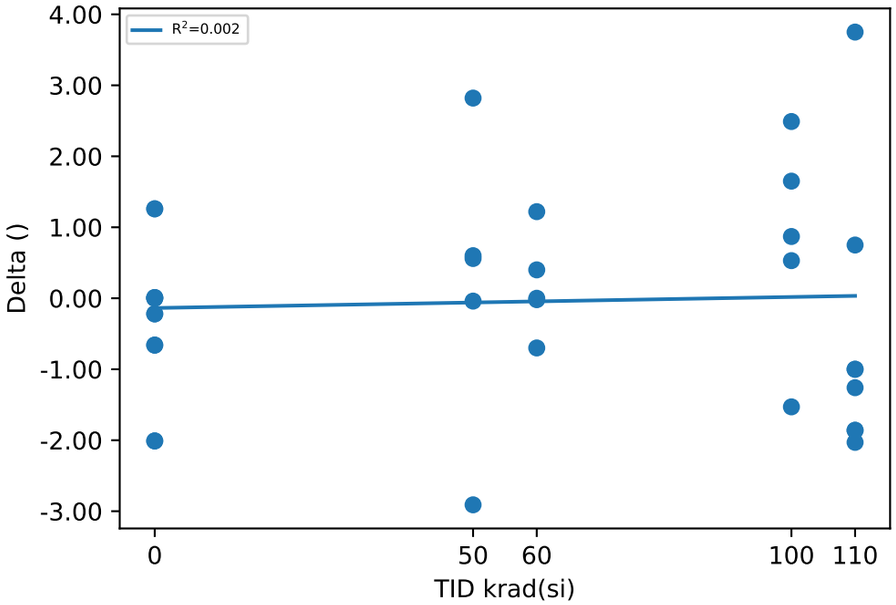
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-4.16	-2.8733	-2.18	1.1154	-3.43	-2.32	-1.29	1.0722	0.04	0.55333	0.89	0.4517
50	-2.17	-0.138	2.16	1.6717	-1.55	0.022	3.36	1.9149	-2.13	0.16	1.7	1.5428
60	-2.8	-1.24	0.54	1.424	-1.5	0.236	3.31	2.0365	0.75	1.476	2.77	0.76035
100	-4.68	-0.452	2.47	2.6836	-4.42	-1.14	1.21	2.222	-1.81	-0.688	0.26	0.83203
110	-2.15	0.136	1.26	1.3647	-2.95	-0.594	0.67	1.4542	-3.91	-0.73	1.53	2.0944

Device Test: 68.23 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH3/3/3///90.9/634//0///@PS_GM_MATCH)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



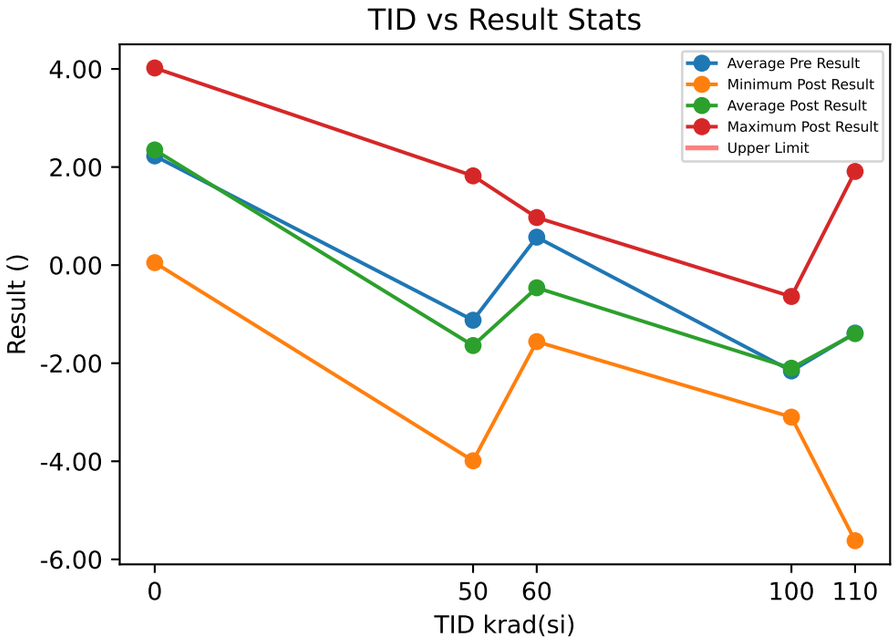
Test Results (No Limits Specified ())

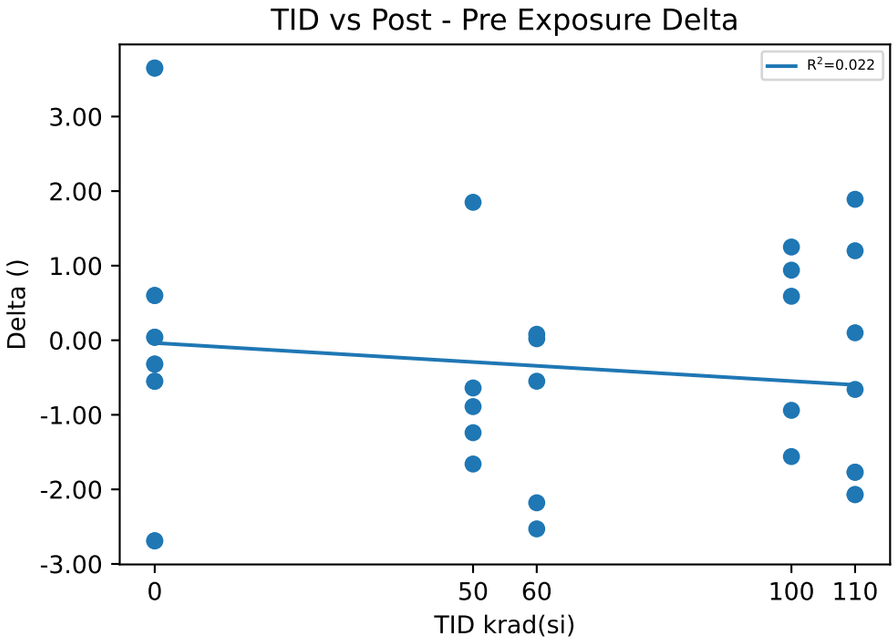
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-2.22	-2.22	0
2	0	CU2	-0.23	-0.89	-0.66
3	0	CU3	-0.98	-1.2	-0.22
11	50	Unbiased-50k	0.93	0.89	-0.04
12	50	Unbiased-50k	1.82	4.64	2.82
13	50	Unbiased-50k	0.36	0.92	0.56
14	50	Unbiased-50k	-1.27	-4.18	-2.91
16	50	Unbiased-50k	1.27	1.87	0.6
17	60	Biased-50k	-1.53	-1.55	-0.02
18	60	Biased-50k	0.01	0.01	0
19	60	Biased-50k	-0.6	-0.2	0.4
20	60	Biased-50k	-0.33	0.89	1.22
21	60	Biased-50k	0.39	-0.31	-0.7
24	100	Unbiased-100k	2.53	3.06	0.53
25	100	Unbiased-100k	-1.26	1.23	2.49
26	100	Unbiased-100k	-1.5	-0.63	0.87
27	100	Unbiased-100k	2.78	1.25	-1.53
28	100	Unbiased-100k	0.29	1.94	1.65
29	110	Biased-100k	3.72	1.69	-2.03
30	110	Biased-100k	-1.52	2.23	3.75
31	110	Biased-100k	-2.52	-1.77	0.75
32	110	Biased-100k	-0.57	-1.83	-1.26
34	110	Biased-100k	-0.91	-1.91	-1

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.22	-1.1433	-0.23	1.005	-2.22	-1.4367	-0.89	0.69587	-0.66	-0.29333	0	0.33606
50	-1.27	0.622	1.82	1.183	-4.18	0.828	4.64	3.1902	-2.91	0.206	2.82	2.0545
60	-1.53	-0.412	0.39	0.72686	-1.55	-0.232	0.89	0.87488	-0.7	0.18	1.22	0.70299
100	-1.5	0.568	2.78	2.0272	-0.63	1.37	3.06	1.343	-1.53	0.802	2.49	1.5071
110	-2.52	-0.36	3.72	2.3981	-1.91	-0.318	2.23	2.0889	-2.03	0.042	3.75	2.3089

Device Test: 68.24 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH4/3/3///90.9/634//0///@PS_GM_MATCH)





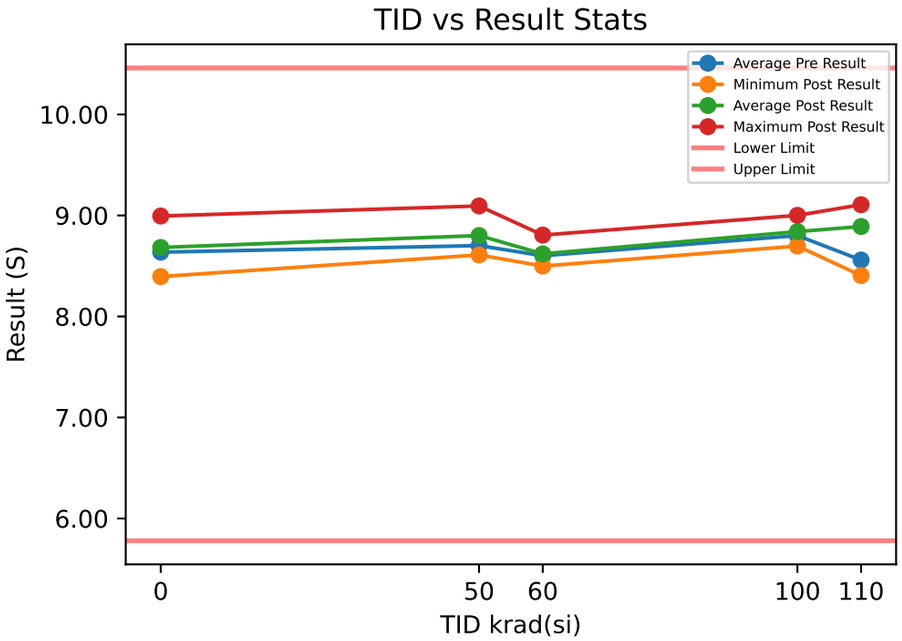
Test Results (No Limits Specified ())

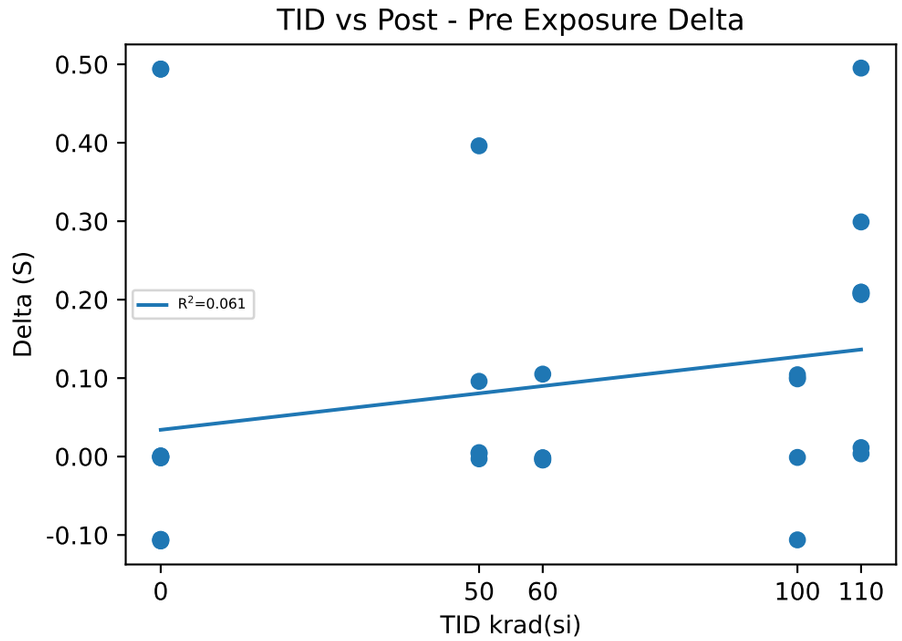
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.9	2.94	0.04
2	0	CU2	3.41	4.01	0.6
3	0	CU3	0.37	0.05	-0.32
11	50	Unbiased-50k	-1.46	-2.7	-1.24
12	50	Unbiased-50k	-3.1	-3.99	-0.89
13	50	Unbiased-50k	0.21	-1.45	-1.66
14	50	Unbiased-50k	2.46	1.82	-0.64
16	50	Unbiased-50k	-3.73	-1.88	1.85
17	60	Biased-50k	-0.33	-0.31	0.02
18	60	Biased-50k	0.03	0.11	0.08
19	60	Biased-50k	0.62	-1.56	-2.18
20	60	Biased-50k	1.01	-1.52	-2.53
21	60	Biased-50k	1.52	0.97	-0.55
24	100	Unbiased-100k	-1.23	-0.64	0.59
25	100	Unbiased-100k	-3.71	-2.46	1.25
26	100	Unbiased-100k	-1.54	-3.1	-1.56
27	100	Unbiased-100k	-3.36	-2.42	0.94
28	100	Unbiased-100k	-0.95	-1.89	-0.94
29	110	Biased-100k	-4.96	-5.62	-0.66
30	110	Biased-100k	-1.67	-1.57	0.1
31	110	Biased-100k	0.02	1.91	1.89
32	110	Biased-100k	-0.62	0.58	1.2
34	110	Biased-100k	0.3	-1.77	-2.07

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.37	2.2267	3.41	1.628	0.05	2.3333	4.01	2.0485	-0.32	0.10667	0.6	0.46361
50	-3.73	-1.124	2.46	2.5216	-3.99	-1.64	1.82	2.1628	-1.66	-0.516	1.85	1.3771
60	-0.33	0.57	1.52	0.74165	-1.56	-0.462	0.97	1.087	-2.53	-1.032	0.08	1.2387
100	-3.71	-2.158	-0.95	1.2802	-3.1	-2.102	-0.64	0.923	-1.56	0.056	1.25	1.2345
110	-4.96	-1.386	0.3	2.1366	-5.62	-1.294	1.91	2.8633	-2.07	0.092	1.89	1.5573

Device Test: 69.17 PS_GM(EA_GMPS|GMPS/CH1/7/7///90.9/634//0///@PS_GM)





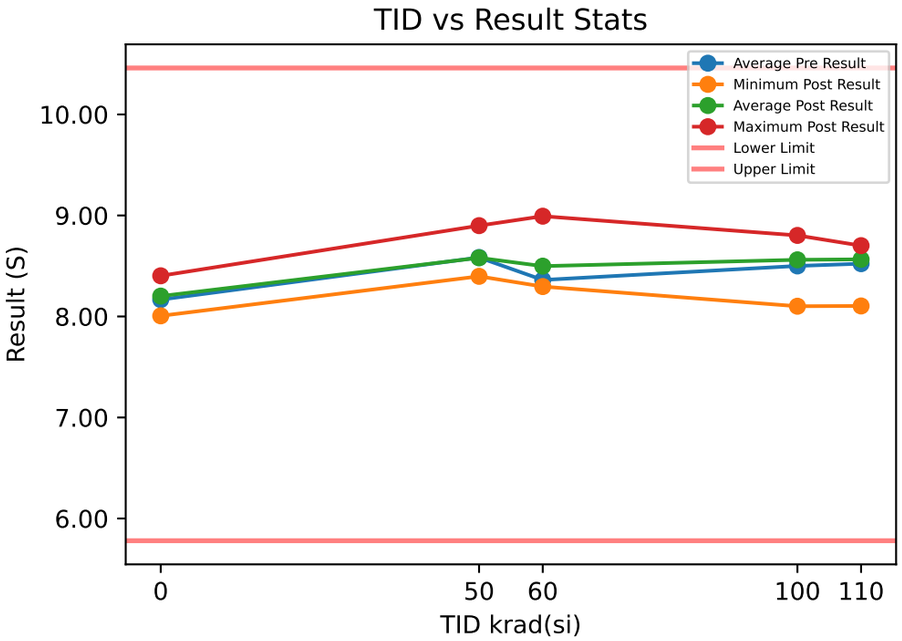
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

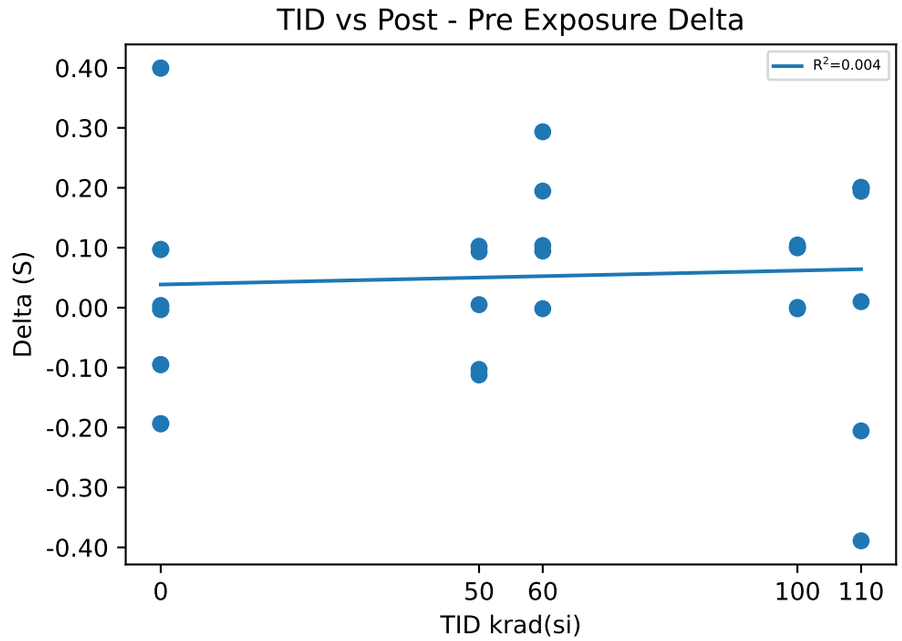
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.5005	8.3948	-0.1057
2	0	CU2	8.6018	8.6015	-0.0003
3	0	CU3	8.8072	8.8057	-0.0015
11	50	Unbiased-50k	8.6045	8.6095	0.005
12	50	Unbiased-50k	8.7032	8.7003	-0.0029
13	50	Unbiased-50k	8.7019	8.7978	0.0959
14	50	Unbiased-50k	8.698	9.0941	0.3961
16	50	Unbiased-50k	8.8006	8.8044	0.0038
17	60	Biased-50k	8.5031	8.4988	-0.0043
18	60	Biased-50k	8.6005	8.5963	-0.0042
19	60	Biased-50k	8.7006	8.699	-0.0016
20	60	Biased-50k	8.7006	8.8057	0.1051
21	60	Biased-50k	8.5005	8.4988	-0.0017
24	100	Unbiased-100k	8.5966	8.6972	0.1006
25	100	Unbiased-100k	8.9046	8.7984	-0.1062
26	100	Unbiased-100k	9.0021	9.001	-0.0011
27	100	Unbiased-100k	8.798	8.9023	0.1043
28	100	Unbiased-100k	8.7019	8.801	0.0991
29	110	Biased-100k	8.594	8.8931	0.2991
30	110	Biased-100k	8.4004	8.4118	0.0114
31	110	Biased-100k	8.4017	8.4052	0.0035
32	110	Biased-100k	8.5005	8.9957	0.4952
34	110	Biased-100k	8.8967	9.1062	0.2095

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.5005	8.6365	8.8072	0.15627	8.3948	8.6007	8.8057	0.20545	-0.1057	-0.035833	-0.0003	0.060509
50	8.6045	8.7016	8.8006	0.069363	8.6095	8.8012	9.0941	0.18217	-0.0029	0.09958	0.3961	0.1707
60	8.5005	8.6011	8.7006	0.099405	8.4988	8.6197	8.8057	0.13292	-0.0043	0.01866	0.1051	0.048339
100	8.5966	8.8006	9.0021	0.1603	8.6972	8.84	9.001	0.11559	-0.1062	0.03934	0.1043	0.092684
110	8.4004	8.5587	8.8967	0.2053	8.4052	8.7624	9.1062	0.33175	0.0035	0.20374	0.4952	0.20686

Device Test: 69.18 PS_GM(EA_GMPS|GMPS/CH2/7/7///90.9/634//0///@PS_GM)





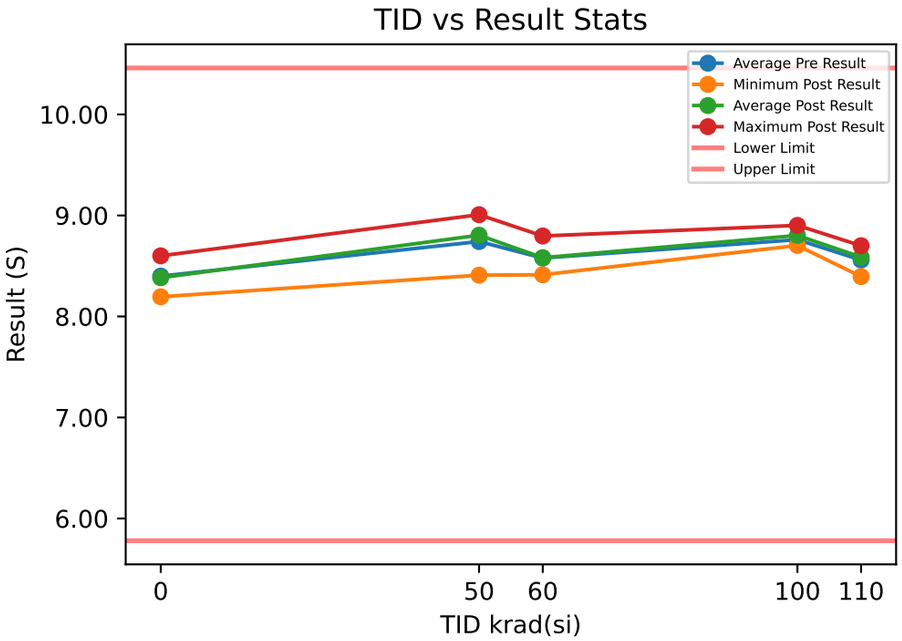
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

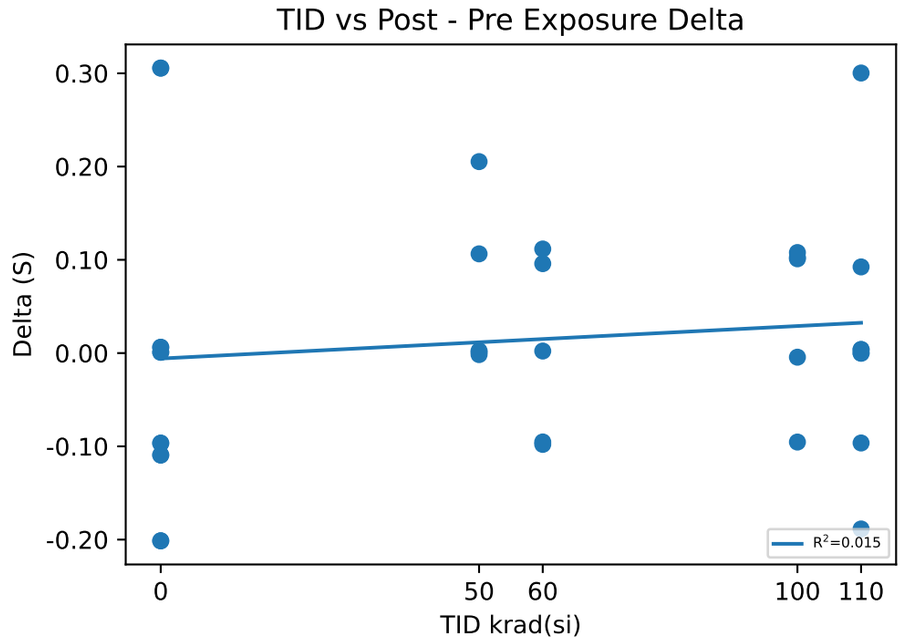
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.0029	8.0062	0.0033
2	0	CU2	8.2003	8.1972	-0.0031
3	0	CU3	8.2977	8.3948	0.0971
11	50	Unbiased-50k	8.8059	8.8992	0.0933
12	50	Unbiased-50k	8.5044	8.5094	0.005
13	50	Unbiased-50k	8.5018	8.3987	-0.1031
14	50	Unbiased-50k	8.5966	8.699	0.1024
16	50	Unbiased-50k	8.5097	8.3974	-0.1123
17	60	Biased-50k	8.2095	8.404	0.1945
18	60	Biased-50k	8.4992	8.4975	-0.0017
19	60	Biased-50k	8.6993	8.9927	0.2934
20	60	Biased-50k	8.1977	8.3013	0.1036
21	60	Biased-50k	8.2016	8.296	0.0944
24	100	Unbiased-100k	8.4978	8.4959	-0.0019
25	100	Unbiased-100k	8.6005	8.7011	0.1006
26	100	Unbiased-100k	8.802	8.8024	0.0004
27	100	Unbiased-100k	8.5992	8.7037	0.1045
28	100	Unbiased-100k	8.0015	8.1014	0.0999
29	110	Biased-100k	8.5031	8.6972	0.1941
30	110	Biased-100k	8.3096	8.104	-0.2056
31	110	Biased-100k	8.3965	8.4065	0.01
32	110	Biased-100k	8.9033	8.5143	-0.389
34	110	Biased-100k	8.5005	8.7011	0.2006

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0029	8.167	8.2977	0.1502	8.0062	8.1994	8.3948	0.19431	-0.0031	0.032433	0.0971	0.056094
50	8.5018	8.5837	8.8059	0.13039	8.3974	8.5807	8.8992	0.21636	-0.1123	-0.00294	0.1024	0.10297
60	8.1977	8.3615	8.6993	0.22835	8.296	8.4983	8.9927	0.28856	-0.0017	0.13684	0.2934	0.11173
100	8.0015	8.5002	8.802	0.29985	8.1014	8.5609	8.8024	0.28006	-0.0019	0.0607	0.1045	0.056129
110	8.3096	8.5226	8.9033	0.22753	8.104	8.4846	8.7011	0.24694	-0.389	-0.03798	0.2006	0.2571

Device Test: 69.19 PS_GM(EA_GMPS|GMPS/CH3/7/7///90.9/634//0///@PS_GM)





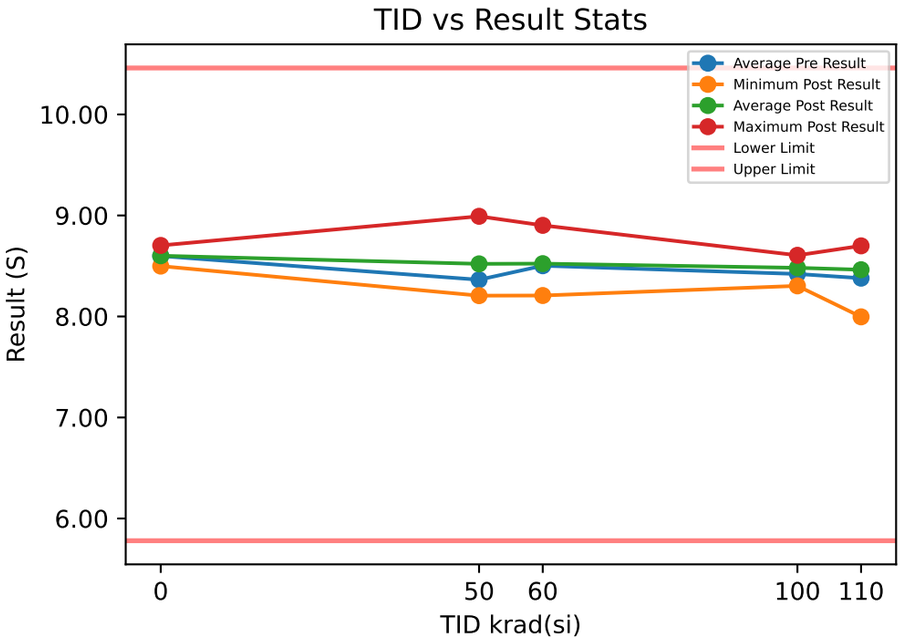
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

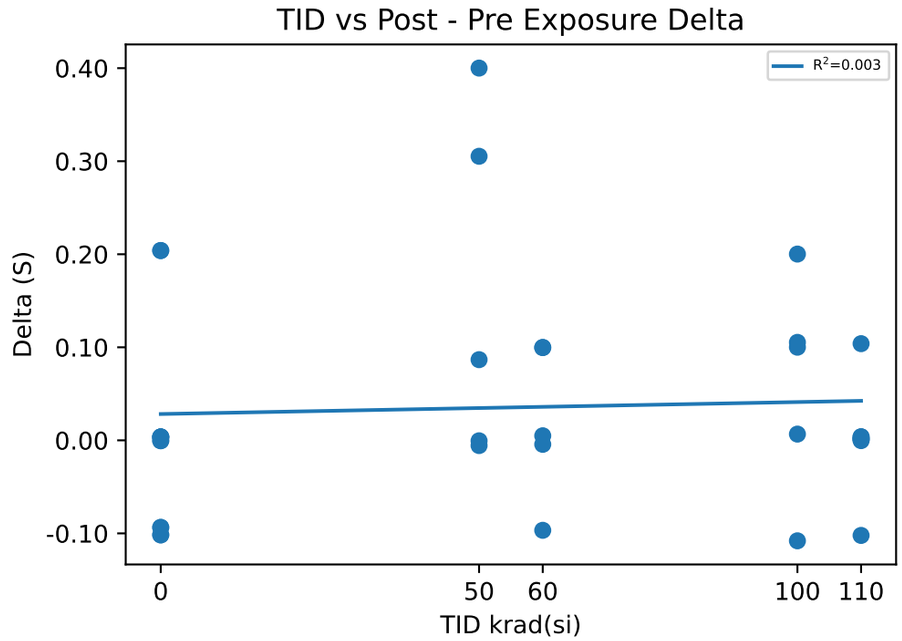
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.2948	8.1982	-0.0966
2	0	CU2	8.3963	8.4025	0.0062
3	0	CU3	8.507	8.5079	0.0009
11	50	Unbiased-50k	8.9023	8.9007	-0.0016
12	50	Unbiased-50k	9.0051	9.0075	0.0024
13	50	Unbiased-50k	8.7995	8.8005	0.001
14	50	Unbiased-50k	8.3027	8.4091	0.1064
16	50	Unbiased-50k	8.6994	8.9047	0.2053
17	60	Biased-50k	8.3014	8.413	0.1116
18	60	Biased-50k	8.5966	8.5013	-0.0953
19	60	Biased-50k	8.7007	8.7966	0.0959
20	60	Biased-50k	8.5953	8.5975	0.0022
21	60	Biased-50k	8.6981	8.6002	-0.0979
24	100	Unbiased-100k	8.9972	8.9018	-0.0954
25	100	Unbiased-100k	8.5979	8.7057	0.1078
26	100	Unbiased-100k	8.7007	8.8018	0.1011
27	100	Unbiased-100k	8.9036	8.8992	-0.0044
28	100	Unbiased-100k	8.6005	8.7031	0.1026
29	110	Biased-100k	8.7969	8.7005	-0.0964
30	110	Biased-100k	8.2988	8.5991	0.3003
31	110	Biased-100k	8.3027	8.3951	0.0924
32	110	Biased-100k	8.7982	8.6096	-0.1886
34	110	Biased-100k	8.5979	8.6017	0.0038

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2948	8.3994	8.507	0.10613	8.1982	8.3695	8.5079	0.15746	-0.0966	-0.029833	0.0062	0.057882
50	8.3027	8.7418	9.0051	0.27066	8.4091	8.8045	9.0075	0.23284	-0.0016	0.0627	0.2053	0.091954
60	8.3014	8.5784	8.7007	0.16327	8.413	8.5817	8.7966	0.14291	-0.0979	0.0033	0.1116	0.10033
100	8.5979	8.76	8.9972	0.18174	8.7031	8.8023	8.9018	0.098059	-0.0954	0.04234	0.1078	0.090175
110	8.2988	8.5589	8.7982	0.24936	8.3951	8.5812	8.7005	0.11226	-0.1886	0.0223	0.3003	0.18782

Device Test: 69.20 PS_GM(EA_GMPS|GMPS/CH4/7/7///90.9/634//0///@PS_GM)





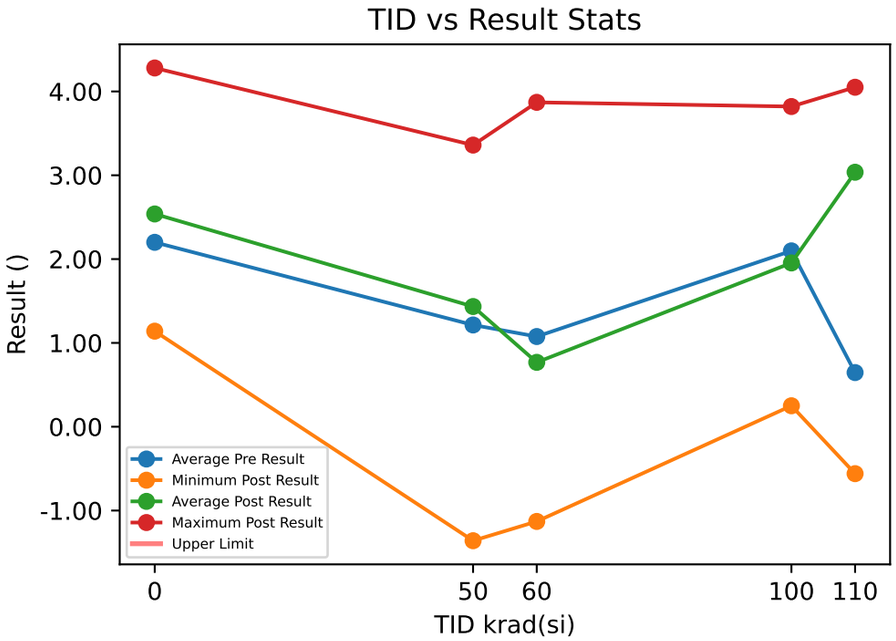
Test Results (Lower Limit = 5.78, Upper Limit = 10.46 (S))

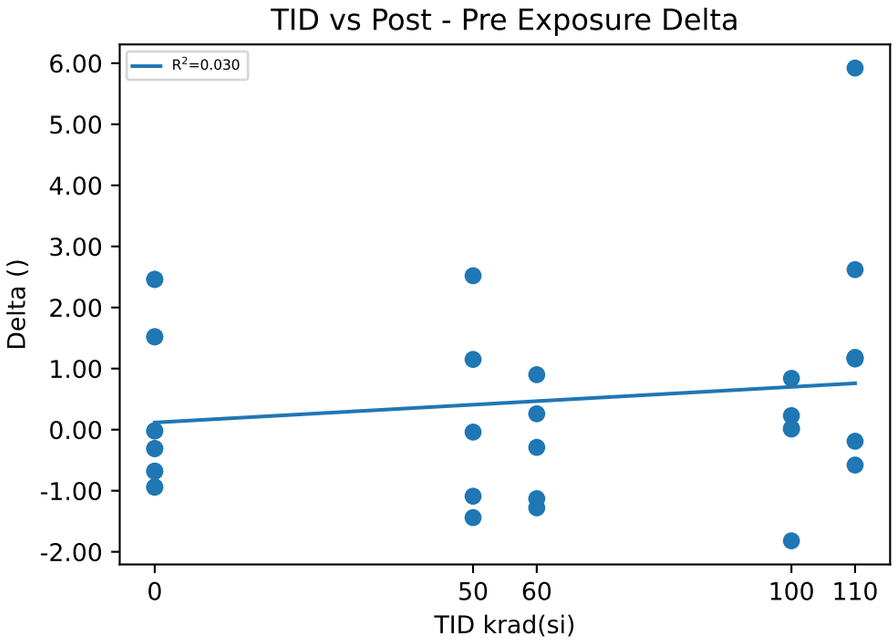
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	8.5966	8.6002	0.0036
2	0	CU2	8.6994	8.703	0.0036
3	0	CU3	8.4991	8.4987	-0.0004
11	50	Unbiased-50k	8.1987	8.504	0.3053
12	50	Unbiased-50k	8.2066	8.2061	-0.0005
13	50	Unbiased-50k	8.503	8.4974	-0.0056
14	50	Unbiased-50k	8.9049	8.9916	0.0867
16	50	Unbiased-50k	8.005	8.4051	0.4001
17	60	Biased-50k	8.2026	8.3023	0.0997
18	60	Biased-50k	8.5017	8.4974	-0.0043
19	60	Biased-50k	8.7007	8.7056	0.0049
20	60	Biased-50k	8.3041	8.2074	-0.0967
21	60	Biased-50k	8.8022	8.902	0.0998
24	100	Unbiased-100k	8.5004	8.6057	0.1053
25	100	Unbiased-100k	8.4029	8.503	0.1001
26	100	Unbiased-100k	8.5057	8.3977	-0.108
27	100	Unbiased-100k	8.3989	8.5991	0.2002
28	100	Unbiased-100k	8.2962	8.3029	0.0067
29	110	Biased-100k	8.0985	7.9963	-0.1022
30	110	Biased-100k	8.001	8.0028	0.0018
31	110	Biased-100k	8.4991	8.603	0.1039
32	110	Biased-100k	8.6994	8.6991	-0.0003
34	110	Biased-100k	8.5979	8.5991	0.0012

Test Statistics (S)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.4991	8.5984	8.6994	0.10016	8.4987	8.6006	8.703	0.10215	-0.0004	0.0022667	0.0036	0.0023094
50	8.005	8.3636	8.9049	0.35102	8.2061	8.5208	8.9916	0.28935	-0.0056	0.1572	0.4001	0.18525
60	8.2026	8.5023	8.8022	0.25417	8.2074	8.5229	8.902	0.28546	-0.0967	0.02068	0.0998	0.082394
100	8.2962	8.4208	8.5057	0.086414	8.3029	8.4817	8.6057	0.13099	-0.108	0.06086	0.2002	0.11659
110	8.001	8.3792	8.6994	0.31087	7.9963	8.3801	8.6991	0.34967	-0.1022	0.00088	0.1039	0.072871

Device Test: 69.21 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH1/7/7///90.9/634//0///@PS_GM_MATCH)





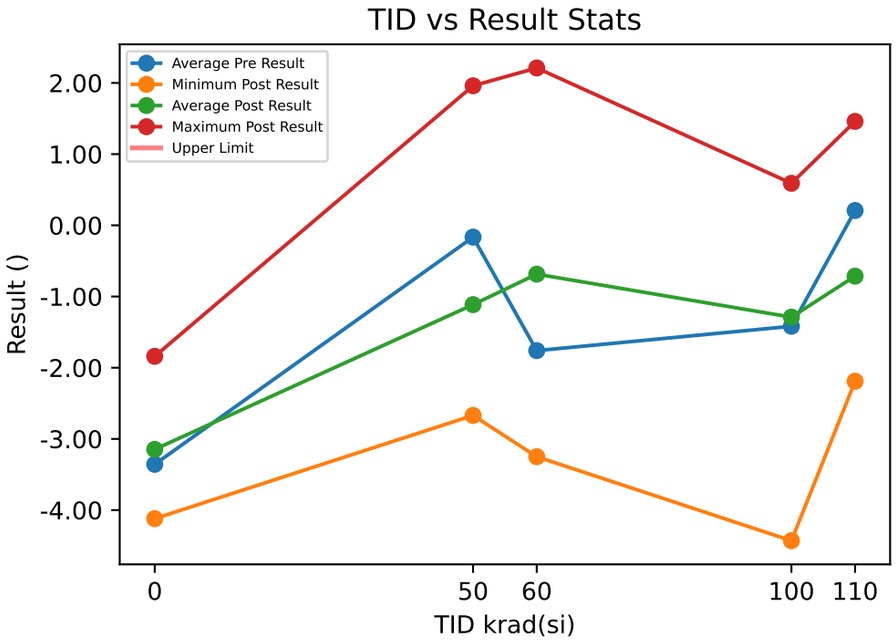
Test Results (No Limits Specified ())

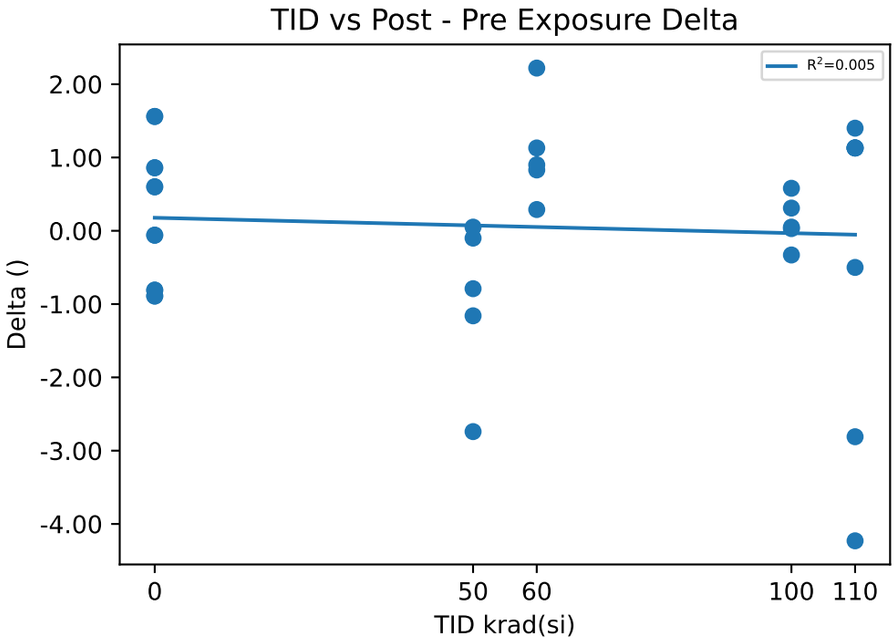
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.82	1.14	-0.68
2	0	CU2	1.5	1.48	-0.02
3	0	CU3	3.28	2.97	-0.31
11	50	Unbiased-50k	-0.27	-1.36	-1.09
12	50	Unbiased-50k	1.14	1.1	-0.04
13	50	Unbiased-50k	0.87	2.02	1.15
14	50	Unbiased-50k	0.84	3.36	2.52
16	50	Unbiased-50k	3.49	2.05	-1.44
17	60	Biased-50k	2.4	1.12	-1.28
18	60	Biased-50k	0.6	0.86	0.26
19	60	Biased-50k	0	-1.13	-1.13
20	60	Biased-50k	2.97	3.87	0.9
21	60	Biased-50k	-0.59	-0.88	-0.29
24	100	Unbiased-100k	-0.59	0.25	0.84
25	100	Unbiased-100k	3.22	1.4	-1.82
26	100	Unbiased-100k	2.85	2.86	0.01
27	100	Unbiased-100k	1.42	1.44	0.02
28	100	Unbiased-100k	3.59	3.82	0.23
29	110	Biased-100k	1.13	3.75	2.62
30	110	Biased-100k	1.79	1.6	-0.19
31	110	Biased-100k	0.02	-0.56	-0.58
32	110	Biased-100k	-2.58	3.34	5.92
34	110	Biased-100k	2.87	4.05	1.18

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5	2.2	3.28	0.94889	1.14	1.8633	2.97	0.97336	-0.68	-0.33667	-0.02	0.33081
50	-0.27	1.214	3.49	1.3826	-1.36	1.434	3.36	1.7572	-1.44	0.22	2.52	1.6351
60	-0.59	1.076	2.97	1.5411	-1.13	0.768	3.87	2.0046	-1.28	-0.308	0.9	0.92232
100	-0.59	2.098	3.59	1.7129	0.25	1.954	3.82	1.3944	-1.82	-0.144	0.84	0.99596
110	-2.58	0.646	2.87	2.0789	-0.56	2.436	4.05	1.9251	-0.58	1.79	5.92	2.6294

Device Test: 69.22 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH2/7/7///90.9/634//0///@PS_GM_MATCH)





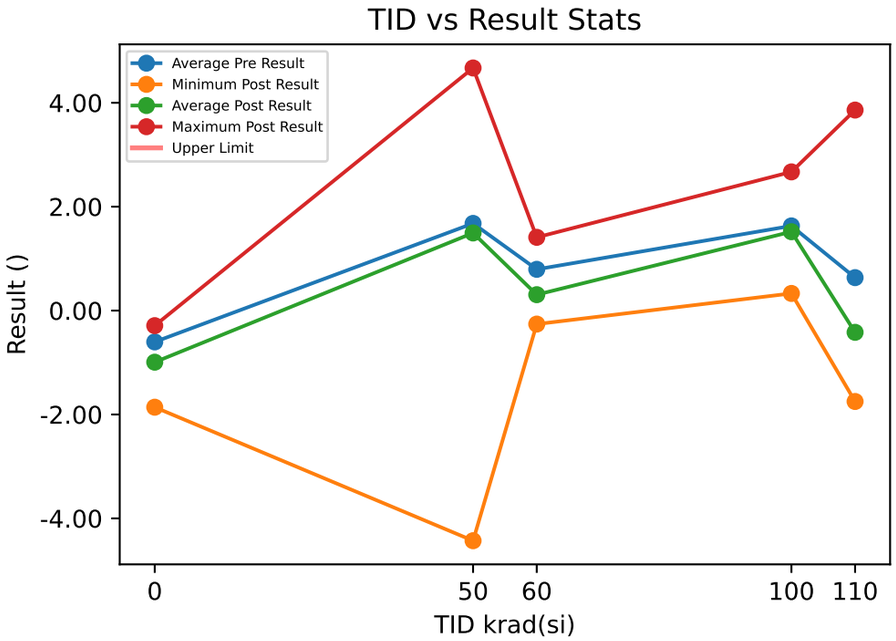
Test Results (No Limits Specified ())

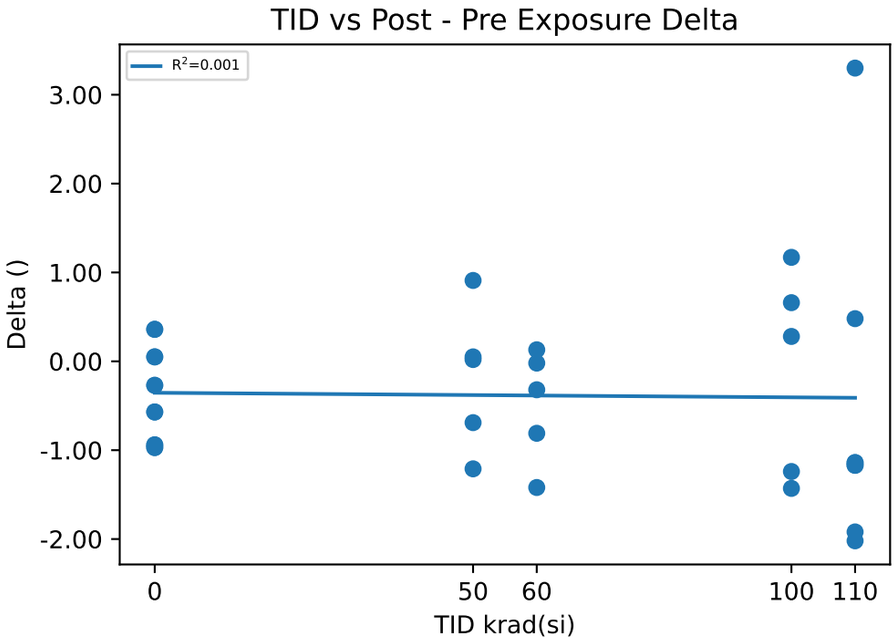
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-4.14	-3.54	0.6
2	0	CU2	-3.23	-3.29	-0.06
3	0	CU3	-2.7	-1.84	0.86
11	50	Unbiased-50k	2.06	1.96	-0.1
12	50	Unbiased-50k	-1.17	-1.12	0.05
13	50	Unbiased-50k	-1.45	-2.61	-1.16
14	50	Unbiased-50k	-0.34	-1.13	-0.79
16	50	Unbiased-50k	0.07	-2.67	-2.74
17	60	Biased-50k	-1.14	-0.01	1.13
18	60	Biased-50k	-0.59	-0.3	0.29
19	60	Biased-50k	-0.01	2.21	2.22
20	60	Biased-50k	-2.98	-2.08	0.9
21	60	Biased-50k	-4.08	-3.25	0.83
24	100	Unbiased-100k	-1.74	-2.07	-0.33
25	100	Unbiased-100k	-0.3	0.28	0.58
26	100	Unbiased-100k	0.56	0.59	0.03
27	100	Unbiased-100k	-0.87	-0.82	0.05
28	100	Unbiased-100k	-4.74	-4.43	0.31
29	110	Biased-100k	0.06	1.46	1.4
30	110	Biased-100k	0.69	-2.12	-2.81
31	110	Biased-100k	-0.04	-0.54	-0.5
32	110	Biased-100k	2.04	-2.19	-4.23
34	110	Biased-100k	-1.71	-0.58	1.13

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-4.14	-3.3567	-2.7	0.72831	-3.54	-2.89	-1.84	0.91788	-0.06	0.46667	0.86	0.47427
50	-1.45	-0.166	2.06	1.3872	-2.67	-1.114	1.96	1.8781	-2.74	-0.948	0.05	1.1176
60	-4.08	-1.76	-0.01	1.7093	-3.25	-0.686	2.21	2.0923	0.29	1.074	2.22	0.7108
100	-4.74	-1.418	0.56	2.0373	-4.43	-1.29	0.59	2.0426	-0.33	0.128	0.58	0.34018
110	-1.71	0.208	2.04	1.3556	-2.19	-0.794	1.46	1.4915	-4.23	-1.002	1.4	2.4625

Device Test: 69.23 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH3/7/7///90.9/634//0///@PS_GM_MATCH)





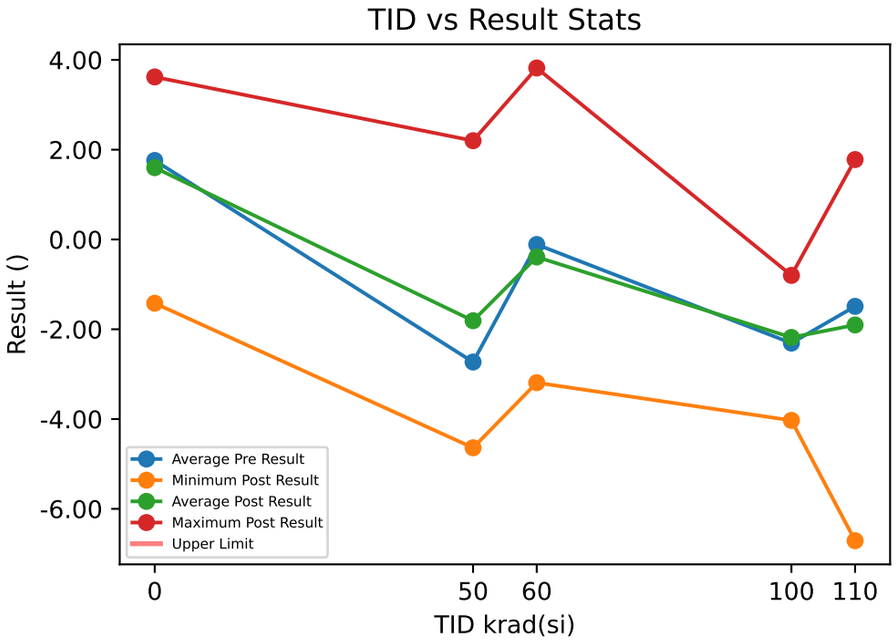
Test Results (No Limits Specified ())

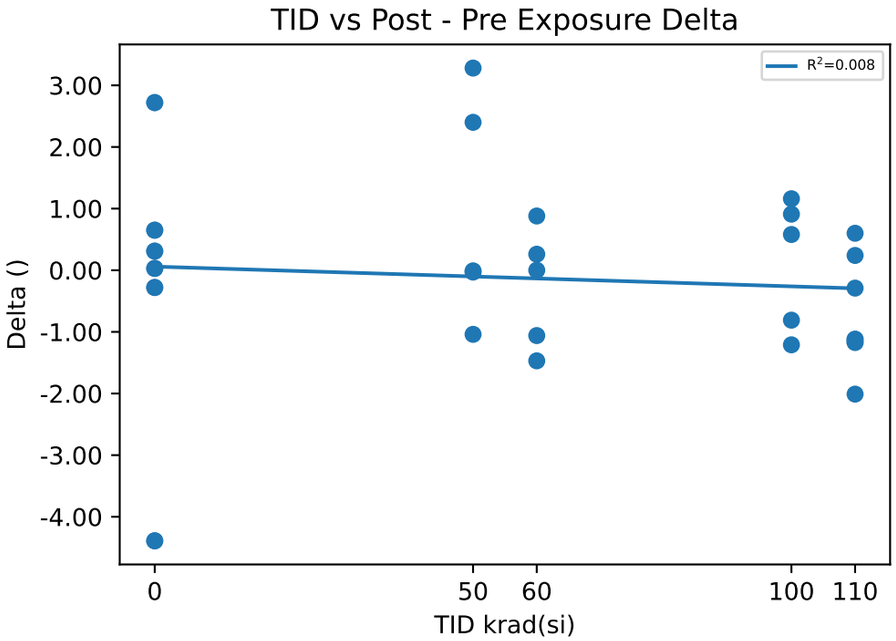
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	-0.65	-1.22	-0.57
2	0	CU2	-0.92	-0.87	0.05
3	0	CU3	-0.24	-0.51	-0.27
11	50	Unbiased-50k	3.18	1.97	-1.21
12	50	Unbiased-50k	4.65	4.67	0.02
13	50	Unbiased-50k	2	2.05	0.05
14	50	Unbiased-50k	-3.74	-4.43	-0.69
16	50	Unbiased-50k	2.3	3.21	0.91
17	60	Biased-50k	-0.03	0.1	0.13
18	60	Biased-50k	0.55	-0.26	-0.81
19	60	Biased-50k	0	-0.02	-0.02
20	60	Biased-50k	1.73	1.41	-0.32
21	60	Biased-50k	1.72	0.3	-1.42
24	100	Unbiased-100k	4.04	2.61	-1.43
25	100	Unbiased-100k	-0.33	0.33	0.66
26	100	Unbiased-100k	-0.59	0.58	1.17
27	100	Unbiased-100k	2.64	1.4	-1.24
28	100	Unbiased-100k	2.39	2.67	0.28
29	110	Biased-100k	3.52	1.5	-2.02
30	110	Biased-100k	0.56	3.86	3.3
31	110	Biased-100k	-1.16	-0.68	0.48
32	110	Biased-100k	0.83	-1.09	-1.92
34	110	Biased-100k	-0.58	-1.72	-1.14

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.92	-0.60333	-0.24	0.34239	-1.22	-0.86667	-0.51	0.35501	-0.57	-0.26333	0.05	0.31005
50	-3.74	1.678	4.65	3.199	-4.43	1.494	4.67	3.4879	-1.21	-0.184	0.91	0.80652
60	-0.03	0.794	1.73	0.8807	-0.26	0.306	1.41	0.6496	-1.42	-0.488	0.13	0.63275
100	-0.59	1.63	4.04	2.011	0.33	1.518	2.67	1.0983	-1.43	-0.112	1.17	1.1622
110	-1.16	0.634	3.52	1.8073	-1.72	0.374	3.86	2.2945	-2.02	-0.26	3.3	2.2276

Device Test: 69.24 PS_GM_MATCH(EA_GMPS|GMPS_Matching/CH4/7/7///90.9/634//0///@PS_GM_MATCH)





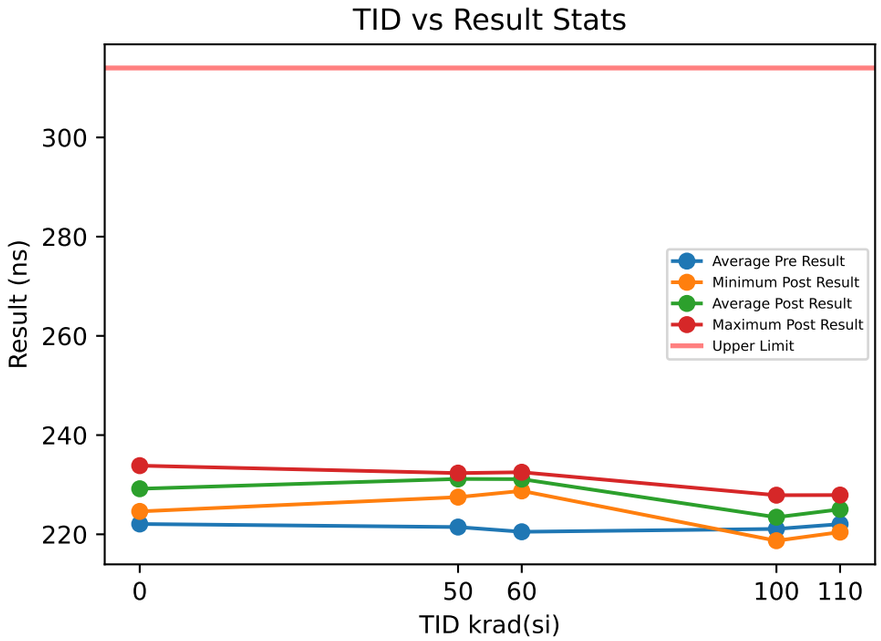
Test Results (No Limits Specified ())

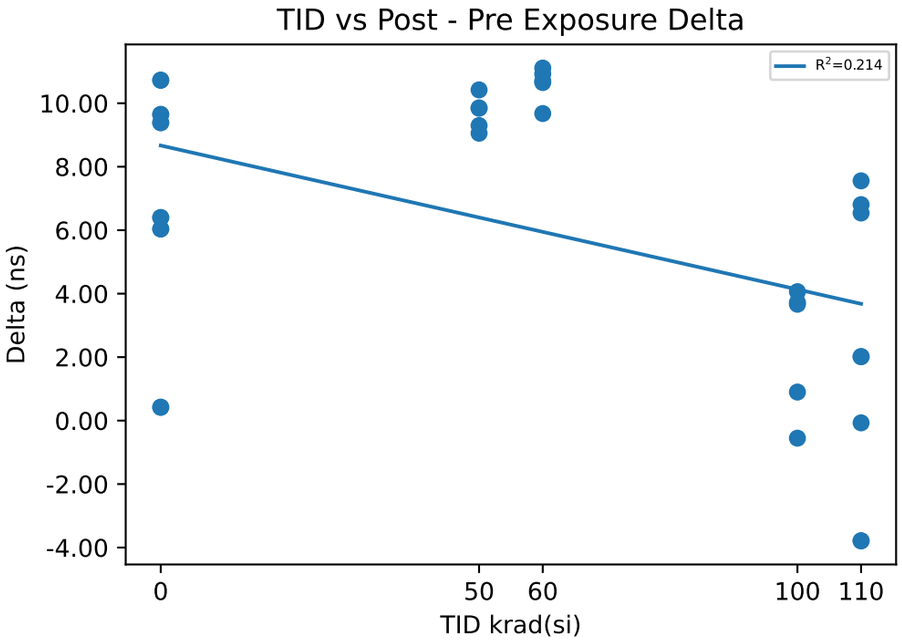
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.97	3.62	0.65
2	0	CU2	2.65	2.68	0.03
3	0	CU3	-0.34	-0.62	-0.28
11	50	Unbiased-50k	-4.97	-2.57	2.4
12	50	Unbiased-50k	-4.63	-4.64	-0.01
13	50	Unbiased-50k	-1.43	-1.46	-0.03
14	50	Unbiased-50k	3.24	2.2	-1.04
16	50	Unbiased-50k	-5.86	-2.58	3.28
17	60	Biased-50k	-1.22	-1.22	0
18	60	Biased-50k	-0.56	-0.3	0.26
19	60	Biased-50k	0	-1.06	-1.06
20	60	Biased-50k	-1.72	-3.19	-1.47
21	60	Biased-50k	2.94	3.82	0.88
24	100	Unbiased-100k	-1.71	-0.8	0.91
25	100	Unbiased-100k	-2.59	-2.01	0.58
26	100	Unbiased-100k	-2.82	-4.03	-1.21
27	100	Unbiased-100k	-3.18	-2.02	1.16
28	100	Unbiased-100k	-1.24	-2.05	-0.81
29	110	Biased-100k	-4.7	-6.71	-2.01
30	110	Biased-100k	-3.05	-3.34	-0.29
31	110	Biased-100k	1.18	1.78	0.6
32	110	Biased-100k	-0.3	-0.06	0.24
34	110	Biased-100k	-0.58	-1.75	-1.17

Test Statistics ()

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.34	1.76	2.97	1.8257	-0.62	1.8933	3.62	2.2268	-0.28	0.13333	0.65	0.47353
50	-5.86	-2.73	3.24	3.7335	-4.64	-1.81	2.2	2.519	-1.04	0.92	3.28	1.8282
60	-1.72	-0.112	2.94	1.8263	-3.19	-0.39	3.82	2.5841	-1.47	-0.278	0.88	0.96696
100	-3.18	-2.308	-1.24	0.80627	-4.03	-2.182	-0.8	1.1617	-1.21	0.126	1.16	1.0666
110	-4.7	-1.49	1.18	2.3511	-6.71	-2.016	1.78	3.244	-2.01	-0.526	0.6	1.0639

vice Test: 72.13 SYNC_SW_DELAY_VIN_3V(EXT_CLOCK|Delay/SYNC_to_SW1/3/3/////1.8///@SYNC_SW_DELAY_VIN_3





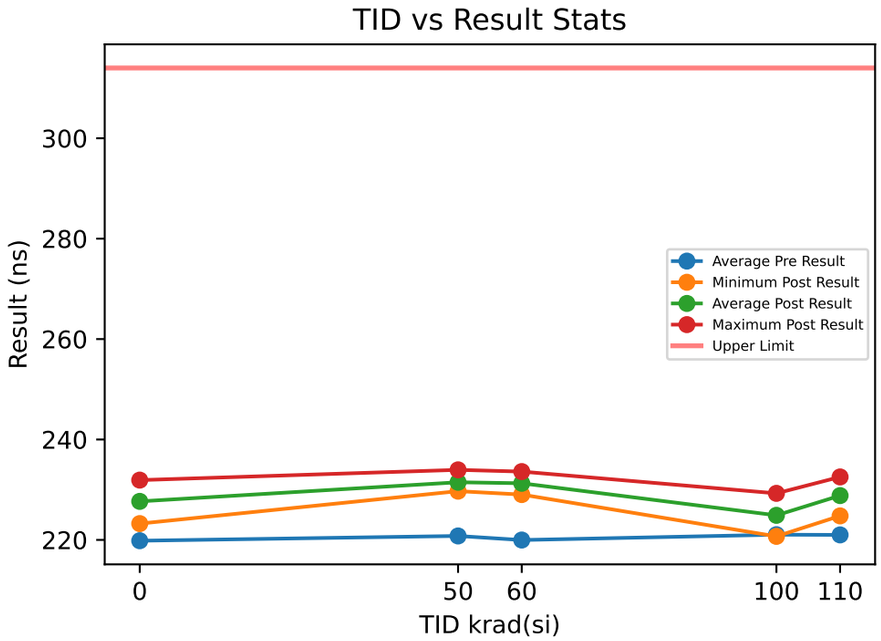
Test Results (Upper Limit = 314.0 (ns))

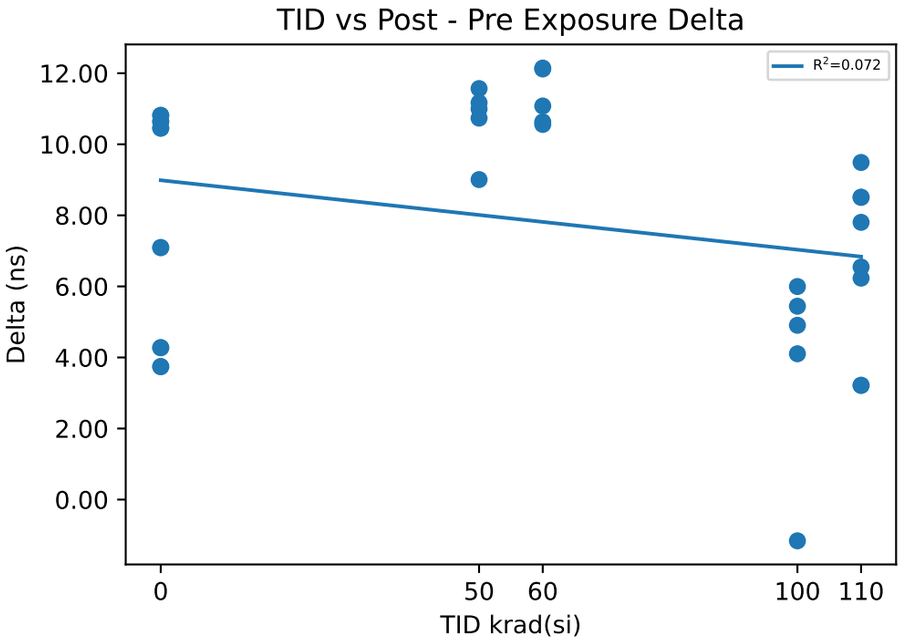
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	219.42	230.15	10.726
2	0	CU2	224.19	233.84	9.6465
3	0	CU3	222.62	232.01	9.3881
11	50	Unbiased-50k	223.28	232.34	9.0552
12	50	Unbiased-50k	221.79	231.64	9.8475
13	50	Unbiased-50k	221.85	232.27	10.421
14	50	Unbiased-50k	217.64	227.49	9.849
16	50	Unbiased-50k	222.74	232.04	9.2972
17	60	Biased-50k	219.08	228.75	9.6753
18	60	Biased-50k	220.75	231.86	11.108
19	60	Biased-50k	220.93	231.86	10.923
20	60	Biased-50k	219.92	230.63	10.701
21	60	Biased-50k	221.86	232.51	10.653
24	100	Unbiased-100k	219.26	218.71	-0.5533
25	100	Unbiased-100k	225.32	226.22	0.8995
26	100	Unbiased-100k	224.22	227.88	3.6668
27	100	Unbiased-100k	218.73	222.45	3.727
28	100	Unbiased-100k	217.9	221.96	4.0622
29	110	Biased-100k	217.84	225.39	7.555
30	110	Biased-100k	221.11	227.91	6.805
31	110	Biased-100k	221.04	227.59	6.5414
32	110	Biased-100k	226.05	225.98	-0.0707
34	110	Biased-100k	224.23	220.44	-3.7879

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	219.42	222.08	224.19	2.4323	230.15	232	233.84	1.8463	9.3881	9.9202	10.726	0.70976
50	217.64	221.46	223.28	2.2248	227.49	231.16	232.34	2.066	9.0552	9.6939	10.421	0.53417
60	219.08	220.51	221.86	1.0555	228.75	231.12	232.51	1.4901	9.6753	10.612	11.108	0.55453
100	217.9	221.08	225.32	3.4191	218.71	223.45	227.88	3.6406	-0.5533	2.3604	4.0622	2.0673
110	217.84	222.05	226.05	3.1774	220.44	225.46	227.91	2.9998	-3.7879	3.4086	7.555	5.0606

vice Test: 72.14 SYNC_SW_DELAY_VIN_3V(EXT_CLOCK|Delay/SYNC_to_SW2/3/3/////1.8///@SYNC_SW_DELAY_VIN_3





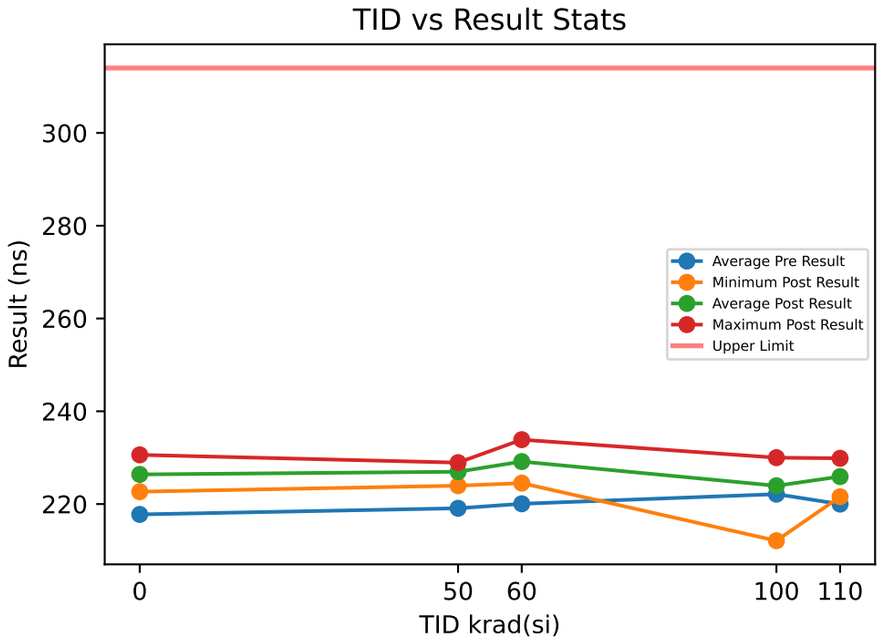
Test Results (Upper Limit = 314.0 (ns))

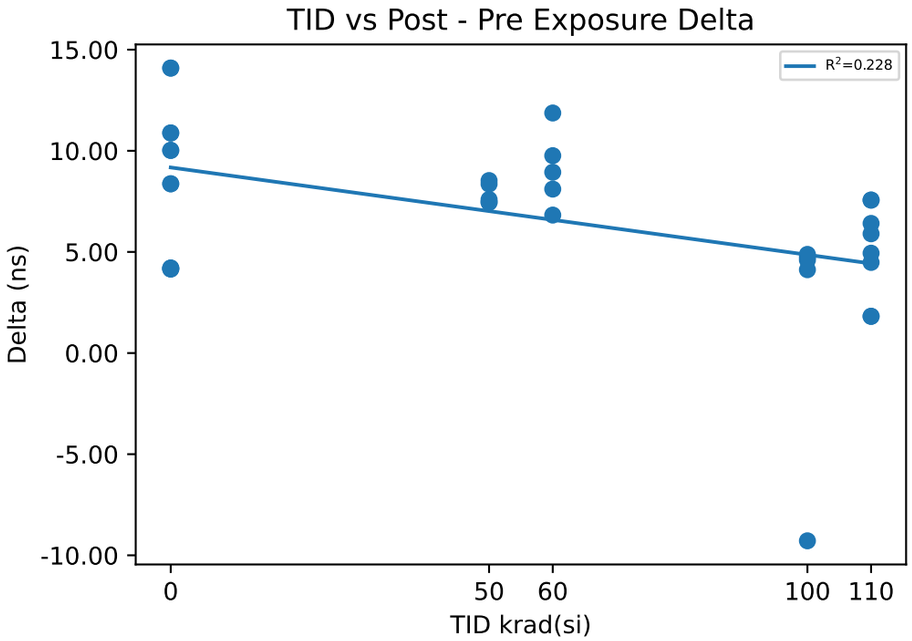
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	218.97	229.61	10.642
2	0	CU2	221.1	231.91	10.813
3	0	CU3	219.44	229.9	10.453
11	50	Unbiased-50k	222.96	233.95	10.996
12	50	Unbiased-50k	222.04	233.21	11.17
13	50	Unbiased-50k	221.59	230.6	9.0062
14	50	Unbiased-50k	218.37	229.94	11.567
16	50	Unbiased-50k	218.97	229.71	10.736
17	60	Biased-50k	218.47	229.03	10.558
18	60	Biased-50k	220.71	232.83	12.119
19	60	Biased-50k	221.46	233.61	12.144
20	60	Biased-50k	219.15	230.23	11.076
21	60	Biased-50k	220.09	230.71	10.629
24	100	Unbiased-100k	221.87	220.71	-1.1603
25	100	Unbiased-100k	223.83	229.27	5.4422
26	100	Unbiased-100k	220.23	224.34	4.104
27	100	Unbiased-100k	222.64	227.55	4.9058
28	100	Unbiased-100k	216.62	222.61	5.9964
29	110	Biased-100k	218.24	224.78	6.5456
30	110	Biased-100k	220.98	227.21	6.2324
31	110	Biased-100k	222.71	230.51	7.803
32	110	Biased-100k	219.04	228.52	9.4881
34	110	Biased-100k	224.03	227.25	3.216

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	218.97	219.84	221.1	1.1151	229.61	230.47	231.91	1.2511	10.453	10.636	10.813	0.17987
50	218.37	220.79	222.96	2.0028	229.71	231.48	233.95	1.9605	9.0062	10.695	11.567	0.99125
60	218.47	219.98	221.46	1.1938	229.03	231.28	233.61	1.8904	10.558	11.305	12.144	0.78013
100	216.62	221.04	223.83	2.7954	220.71	224.9	229.27	3.5097	-1.1603	3.8576	5.9964	2.8907
110	218.24	221	224.03	2.43	224.78	227.66	230.51	2.0939	3.216	6.657	9.4881	2.3109

vice Test: 72.15 SYNC_SW_DELAY_VIN_3V(EXT_CLOCK|Delay/SYNC_to_SW3/3/3/////1.8///@SYNC_SW_DELAY_VIN_3





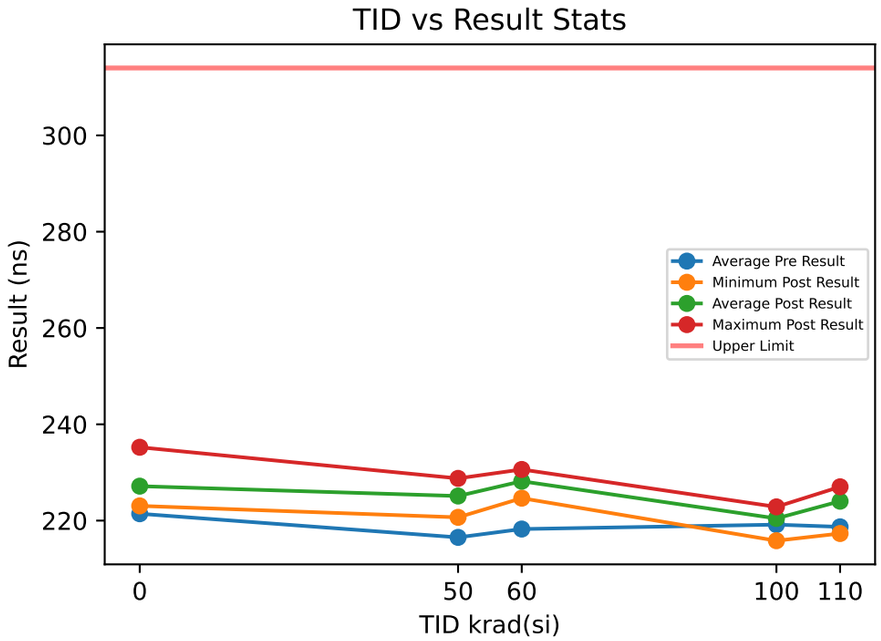
Test Results (Upper Limit = 314.0 (ns))

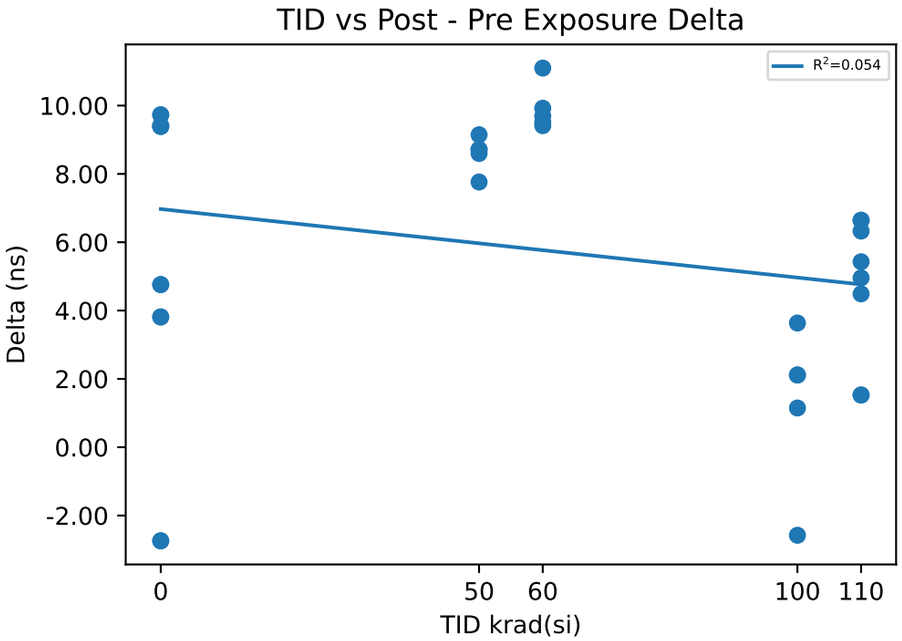
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	220.58	230.61	10.022
2	0	CU2	214.2	228.29	14.09
3	0	CU3	218.51	226.88	8.3685
11	50	Unbiased-50k	218.95	226.4	7.4446
12	50	Unbiased-50k	221.34	228.93	7.5924
13	50	Unbiased-50k	216.49	223.96	7.4683
14	50	Unbiased-50k	219.63	227.99	8.3568
16	50	Unbiased-50k	219.04	227.57	8.5286
17	60	Biased-50k	216.41	224.52	8.1066
18	60	Biased-50k	220.11	231.98	11.869
19	60	Biased-50k	216.27	226.03	9.7594
20	60	Biased-50k	222.56	229.38	6.8221
21	60	Biased-50k	224.94	233.88	8.9405
24	100	Unbiased-100k	221.38	212.1	-9.2836
25	100	Unbiased-100k	218.47	223.06	4.5966
26	100	Unbiased-100k	225.88	230	4.1209
27	100	Unbiased-100k	224.3	229.03	4.7307
28	100	Unbiased-100k	220.66	225.54	4.8778
29	110	Biased-100k	220.88	227.29	6.409
30	110	Biased-100k	216.64	221.58	4.9371
31	110	Biased-100k	219.85	225.75	5.8979
32	110	Biased-100k	220.3	224.78	4.4809
34	110	Biased-100k	222.3	224.12	1.8169

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	214.2	217.77	220.58	3.2546	226.88	228.59	230.61	1.8815	8.3685	10.827	14.09	2.9444
50	216.49	219.09	221.34	1.7419	223.96	226.97	228.93	1.9133	7.4446	7.8781	8.5286	0.52196
60	216.27	220.06	224.94	3.7991	224.52	229.16	233.88	3.9257	6.8221	9.0995	11.869	1.8909
100	218.47	222.14	225.88	2.9531	212.1	223.95	230	7.1794	-9.2836	1.8085	4.8778	6.2072
110	216.64	219.99	222.3	2.091	221.58	224.7	227.29	2.1155	1.8169	4.7084	6.409	1.7869

vice Test: 72.16 SYNC_SW_DELAY_VIN_3V(EXT_CLOCK|Delay/SYNC_to_SW4/3/3/////1.8///@SYNC_SW_DELAY_VIN_3





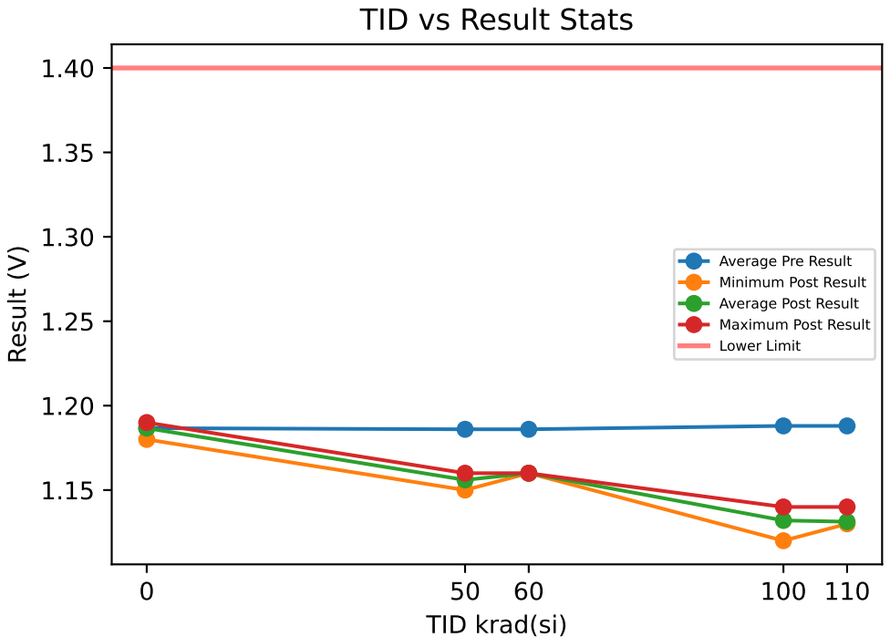
Test Results (Upper Limit = 314.0 (ns))

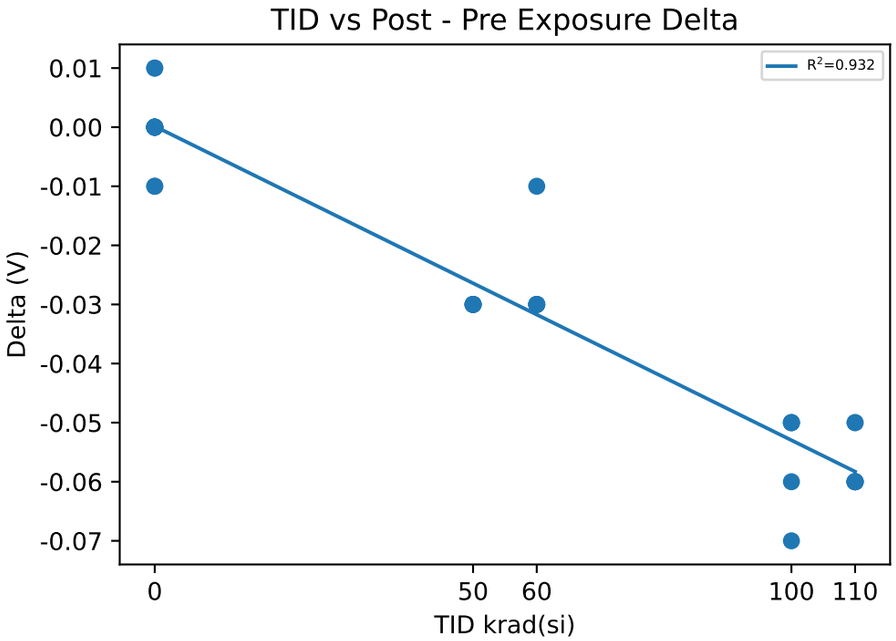
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	219.19	228.92	9.7296
2	0	CU2	219.25	228.66	9.4124
3	0	CU3	225.84	235.23	9.3898
11	50	Unbiased-50k	217.39	226.54	9.1466
12	50	Unbiased-50k	216.78	225.49	8.7151
13	50	Unbiased-50k	221.01	228.77	7.763
14	50	Unbiased-50k	215.45	224.05	8.598
16	50	Unbiased-50k	211.96	220.68	8.7165
17	60	Biased-50k	215.25	224.66	9.4124
18	60	Biased-50k	220.21	230.13	9.9233
19	60	Biased-50k	216.37	227.47	11.098
20	60	Biased-50k	220.93	230.62	9.6932
21	60	Biased-50k	218.49	228	9.5132
24	100	Unbiased-100k	218.4	215.82	-2.578
25	100	Unbiased-100k	220.74	222.85	2.1147
26	100	Unbiased-100k	217.02	219.13	2.1126
27	100	Unbiased-100k	221.6	222.75	1.1475
28	100	Unbiased-100k	218.06	221.7	3.6345
29	110	Biased-100k	220.46	226.79	6.3273
30	110	Biased-100k	212.36	217.32	4.9559
31	110	Biased-100k	219.04	224.47	5.4285
32	110	Biased-100k	221.29	225.78	4.4888
34	110	Biased-100k	220.38	221.91	1.5278

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	219.19	221.43	225.84	3.8235	228.66	230.94	235.23	3.7212	9.3898	9.5106	9.7296	0.19
50	211.96	216.52	221.01	3.2727	220.68	225.11	228.77	3.0131	7.763	8.5878	9.1466	0.50632
60	215.25	218.25	220.93	2.4314	224.66	228.18	230.62	2.3834	9.4124	9.9281	11.098	0.68244
100	217.02	219.16	221.6	1.9265	215.82	220.45	222.85	2.9907	-2.578	1.2863	3.6345	2.3364
110	212.36	218.71	221.29	3.637	217.32	223.25	226.79	3.7879	1.5278	4.5457	6.3273	1.8188

Device Test: 72.17 SYNC_SW_VIH_VIN_3V(EXT_CLOCK|VIH/SYNC/3/3/////1.8///@SYNC_SW_VIH_VIN_3V)





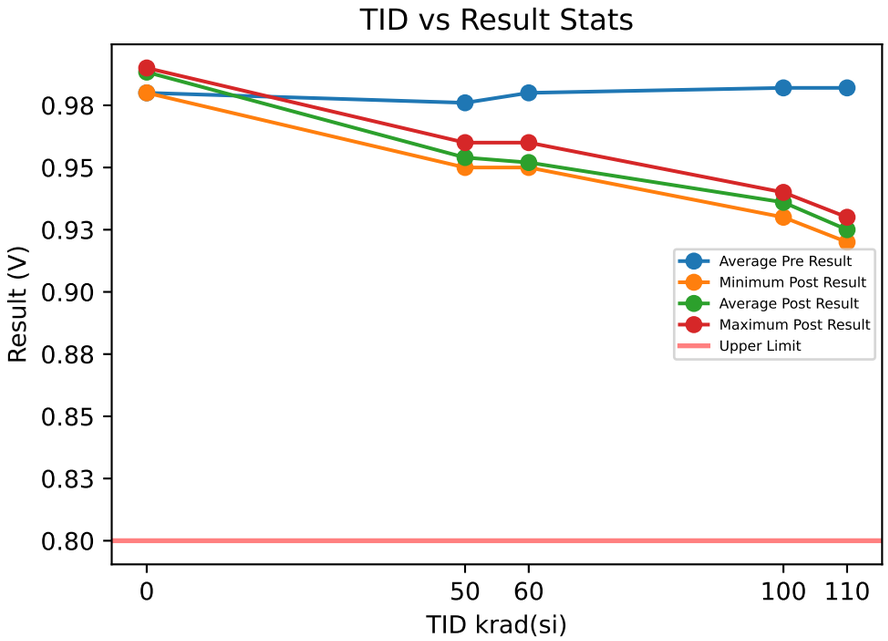
Test Results (Lower Limit = 1.4 (V))

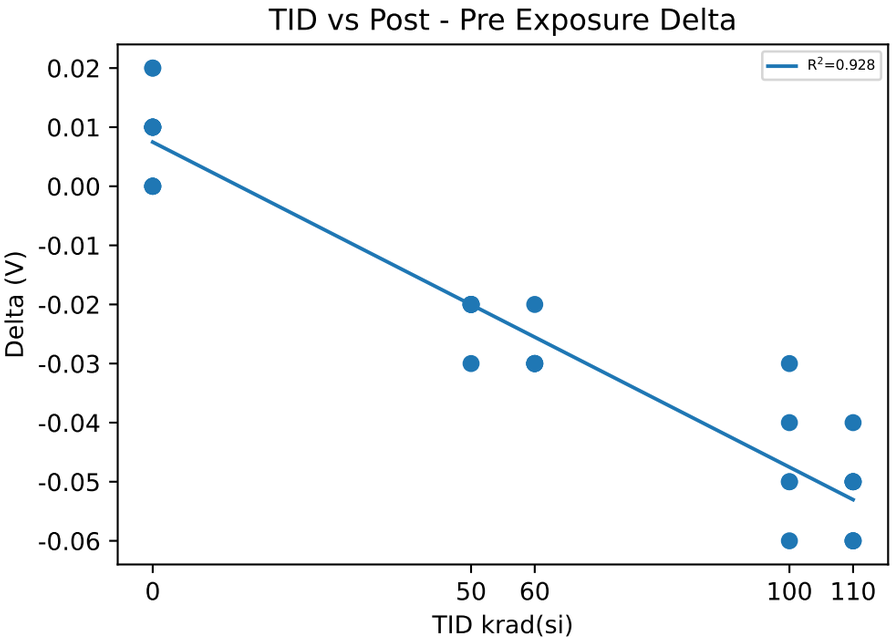
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.19	1.19	0
2	0	CU2	1.19	1.19	0
3	0	CU3	1.18	1.18	0
11	50	Unbiased-50k	1.18	1.15	-0.03
12	50	Unbiased-50k	1.19	1.16	-0.03
13	50	Unbiased-50k	1.19	1.16	-0.03
14	50	Unbiased-50k	1.19	1.16	-0.03
16	50	Unbiased-50k	1.18	1.15	-0.03
17	60	Biased-50k	1.19	1.16	-0.03
18	60	Biased-50k	1.19	1.16	-0.03
19	60	Biased-50k	1.17	1.16	-0.01
20	60	Biased-50k	1.19	1.16	-0.03
21	60	Biased-50k	1.19	1.16	-0.03
24	100	Unbiased-100k	1.19	1.14	-0.05
25	100	Unbiased-100k	1.19	1.14	-0.05
26	100	Unbiased-100k	1.19	1.13	-0.06
27	100	Unbiased-100k	1.19	1.12	-0.07
28	100	Unbiased-100k	1.18	1.13	-0.05
29	110	Biased-100k	1.19	1.14	-0.05
30	110	Biased-100k	1.19	1.13	-0.06
31	110	Biased-100k	1.18	1.13	-0.05
32	110	Biased-100k	1.19	1.13	-0.06
34	110	Biased-100k	1.19	1.13	-0.06

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.18	1.1867	1.19	0.0057735	1.18	1.1867	1.19	0.0057735	0	0	0	0
50	1.18	1.186	1.19	0.0054772	1.15	1.156	1.16	0.0054772	-0.03	-0.03	-0.03	0
60	1.17	1.186	1.19	0.0089443	1.16	1.16	1.16	0	-0.03	-0.026	-0.01	0.0089443
100	1.18	1.188	1.19	0.0044721	1.12	1.132	1.14	0.0083666	-0.07	-0.056	-0.05	0.0089443
110	1.18	1.188	1.19	0.0044721	1.13	1.132	1.14	0.0044721	-0.06	-0.056	-0.05	0.0054772

Device Test: 72.18 SYNC_VIL(EXT_CLOCK|VIL/SYNC/3/3/////1.8///@SYNC_VIL)





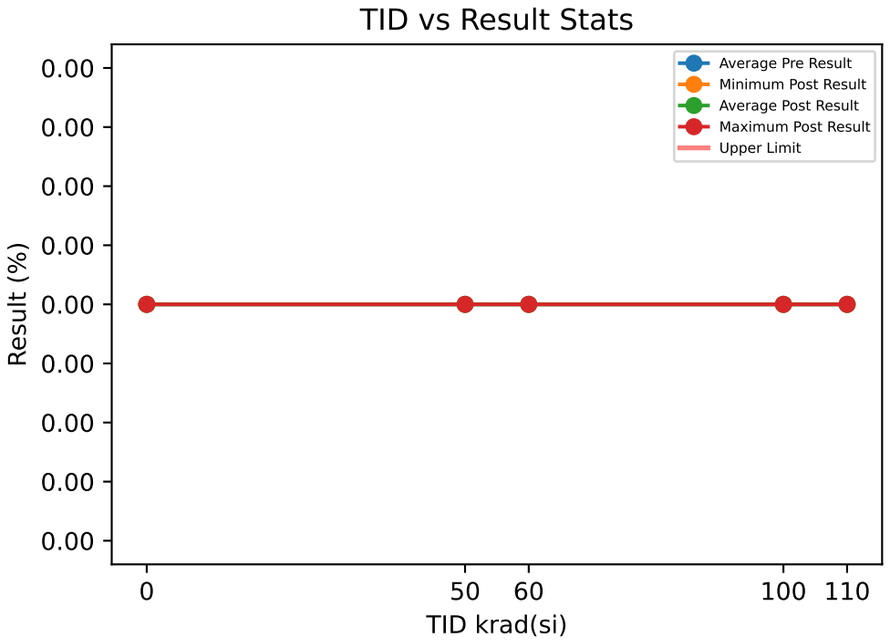
Test Results (Upper Limit = 0.8 (V))

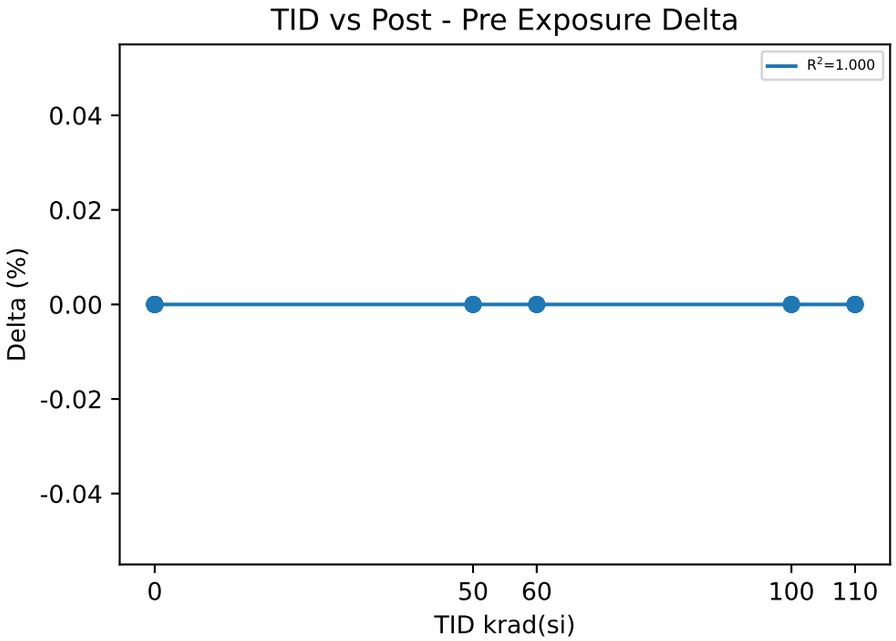
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	0.97	0.99	0.02
2	0	CU2	0.99	0.99	0
3	0	CU3	0.98	0.99	0.01
11	50	Unbiased-50k	0.98	0.95	-0.03
12	50	Unbiased-50k	0.97	0.95	-0.02
13	50	Unbiased-50k	0.98	0.96	-0.02
14	50	Unbiased-50k	0.97	0.95	-0.02
16	50	Unbiased-50k	0.98	0.96	-0.02
17	60	Biased-50k	0.98	0.95	-0.03
18	60	Biased-50k	0.99	0.96	-0.03
19	60	Biased-50k	0.98	0.95	-0.03
20	60	Biased-50k	0.98	0.95	-0.03
21	60	Biased-50k	0.97	0.95	-0.02
24	100	Unbiased-100k	0.99	0.94	-0.05
25	100	Unbiased-100k	0.97	0.94	-0.03
26	100	Unbiased-100k	0.99	0.94	-0.05
27	100	Unbiased-100k	0.99	0.93	-0.06
28	100	Unbiased-100k	0.97	0.93	-0.04
29	110	Biased-100k	0.99	0.93	-0.06
30	110	Biased-100k	0.99	0.93	-0.06
31	110	Biased-100k	0.97	0.93	-0.04
32	110	Biased-100k	0.99	0.93	-0.06
34	110	Biased-100k	0.97	0.92	-0.05

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.97	0.98	0.99	0.01	0.99	0.99	0.99	0	0	0.01	0.02	0.01
50	0.97	0.976	0.98	0.0054772	0.95	0.954	0.96	0.0054772	-0.03	-0.022	-0.02	0.0044721
60	0.97	0.98	0.99	0.0070711	0.95	0.952	0.96	0.0044721	-0.03	-0.028	-0.02	0.0044721
100	0.97	0.982	0.99	0.010954	0.93	0.936	0.94	0.0054772	-0.06	-0.046	-0.03	0.011402
110	0.97	0.982	0.99	0.010954	0.92	0.928	0.93	0.0044721	-0.06	-0.054	-0.04	0.0089443

Test: 72.19 SYNC_IN_DUTY_CYCLE_LOW(EXT_CLOCK|GNG_DutyCyc40Pct/SYNC/3/3/////1.8///@SYNC_IN_DUTY_CYCL





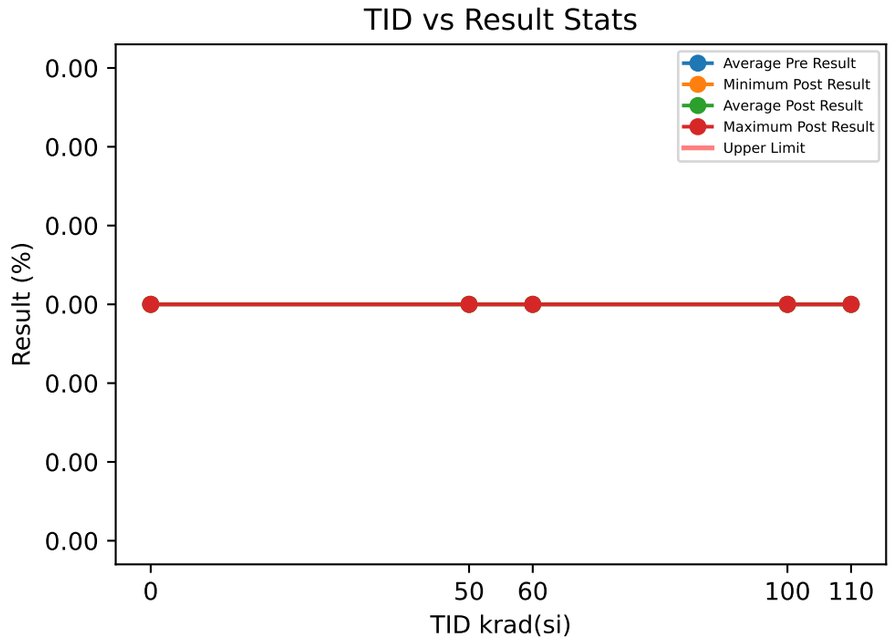
Test Results (No Limits Specified (%))

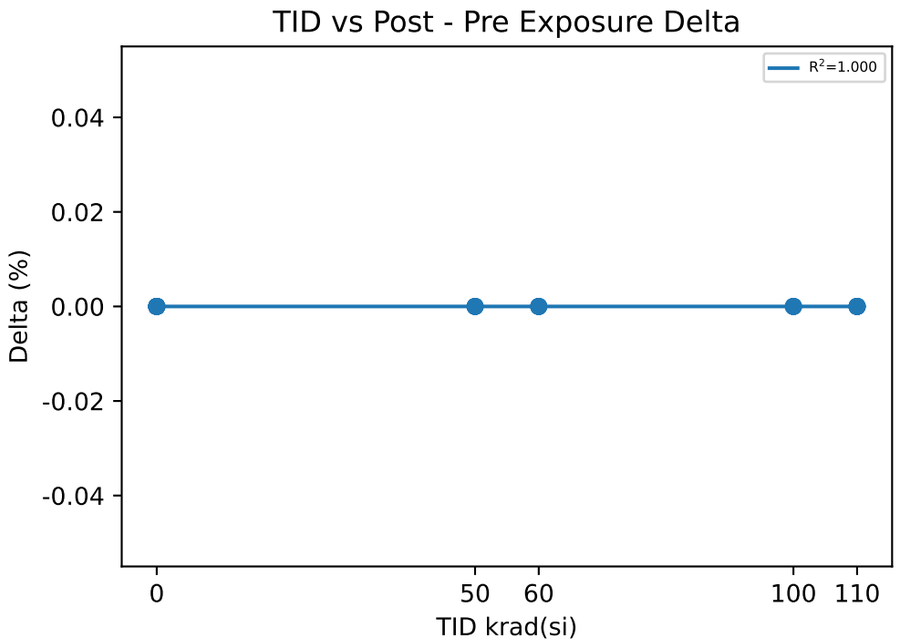
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	4e-13	4e-13	0
2	0	CU2	4e-13	4e-13	0
3	0	CU3	4e-13	4e-13	0
11	50	Unbiased-50k	4e-13	4e-13	0
12	50	Unbiased-50k	4e-13	4e-13	0
13	50	Unbiased-50k	4e-13	4e-13	0
14	50	Unbiased-50k	4e-13	4e-13	0
16	50	Unbiased-50k	4e-13	4e-13	0
17	60	Biased-50k	4e-13	4e-13	0
18	60	Biased-50k	4e-13	4e-13	0
19	60	Biased-50k	4e-13	4e-13	0
20	60	Biased-50k	4e-13	4e-13	0
21	60	Biased-50k	4e-13	4e-13	0
24	100	Unbiased-100k	4e-13	4e-13	0
25	100	Unbiased-100k	4e-13	4e-13	0
26	100	Unbiased-100k	4e-13	4e-13	0
27	100	Unbiased-100k	4e-13	4e-13	0
28	100	Unbiased-100k	4e-13	4e-13	0
29	110	Biased-100k	4e-13	4e-13	0
30	110	Biased-100k	4e-13	4e-13	0
31	110	Biased-100k	4e-13	4e-13	0
32	110	Biased-100k	4e-13	4e-13	0
34	110	Biased-100k	4e-13	4e-13	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
50	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
60	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
100	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
110	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0

Test: 72.20 SYNC_IN_DUTY_CYCLE_HIGH(EXT_CLOCK|GNG_DutyCyc60Pct/SYNC/3/3/////1.8///@SYNC_IN_DUTY_CYCL





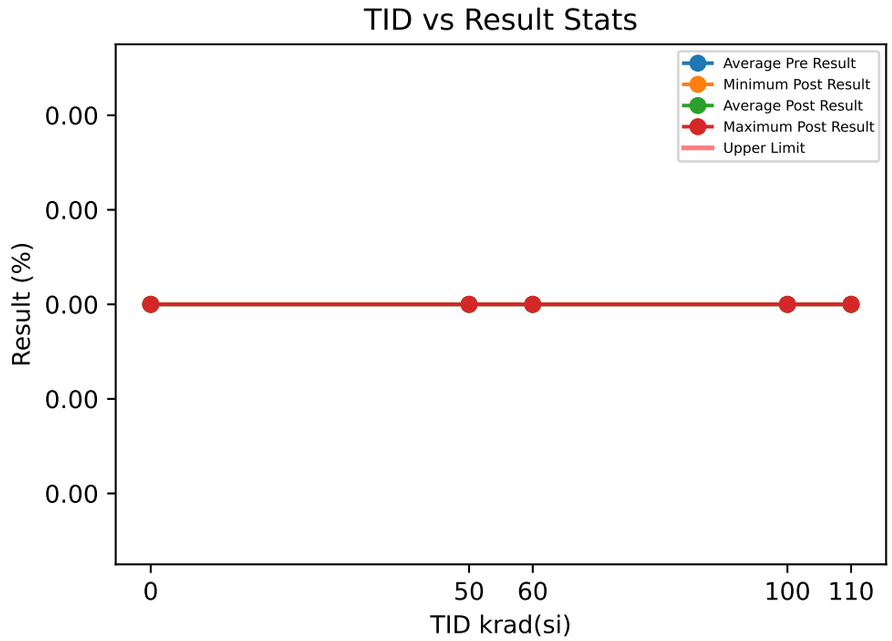
Test Results (No Limits Specified (%))

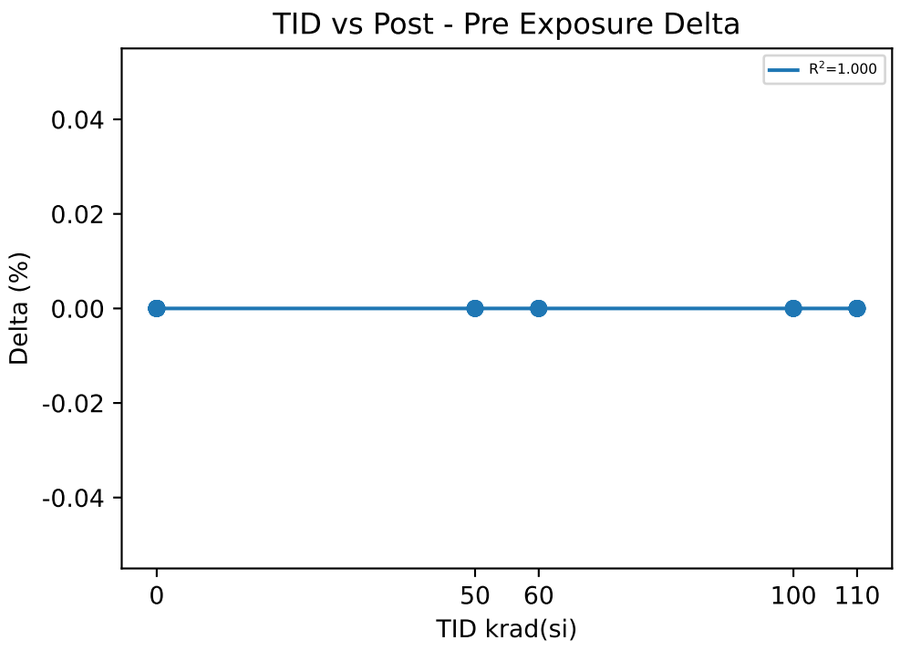
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6e-13	6e-13	0
2	0	CU2	6e-13	6e-13	0
3	0	CU3	6e-13	6e-13	0
11	50	Unbiased-50k	6e-13	6e-13	0
12	50	Unbiased-50k	6e-13	6e-13	0
13	50	Unbiased-50k	6e-13	6e-13	0
14	50	Unbiased-50k	6e-13	6e-13	0
16	50	Unbiased-50k	6e-13	6e-13	0
17	60	Biased-50k	6e-13	6e-13	0
18	60	Biased-50k	6e-13	6e-13	0
19	60	Biased-50k	6e-13	6e-13	0
20	60	Biased-50k	6e-13	6e-13	0
21	60	Biased-50k	6e-13	6e-13	0
24	100	Unbiased-100k	6e-13	6e-13	0
25	100	Unbiased-100k	6e-13	6e-13	0
26	100	Unbiased-100k	6e-13	6e-13	0
27	100	Unbiased-100k	6e-13	6e-13	0
28	100	Unbiased-100k	6e-13	6e-13	0
29	110	Biased-100k	6e-13	6e-13	0
30	110	Biased-100k	6e-13	6e-13	0
31	110	Biased-100k	6e-13	6e-13	0
32	110	Biased-100k	6e-13	6e-13	0
34	110	Biased-100k	6e-13	6e-13	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
50	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
60	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
100	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
110	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0

t: 72.21 SYNC_IN_DUTY_CYCLE_RANGE(EXT_CLOCK|GNG_DutyCycRange/SYNC/3/3/////1.8///@SYNC_IN_DUTY_CYCL





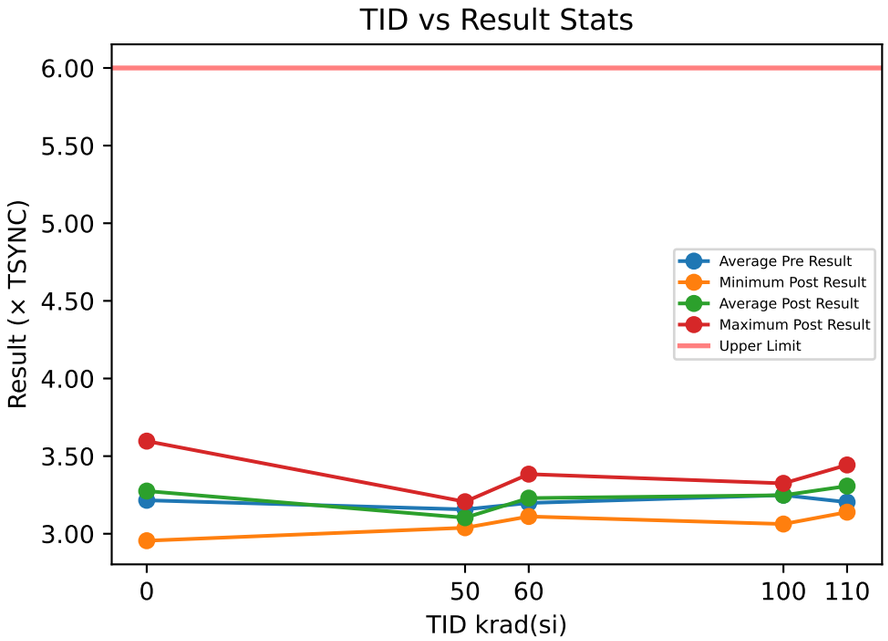
Test Results (No Limits Specified (%))

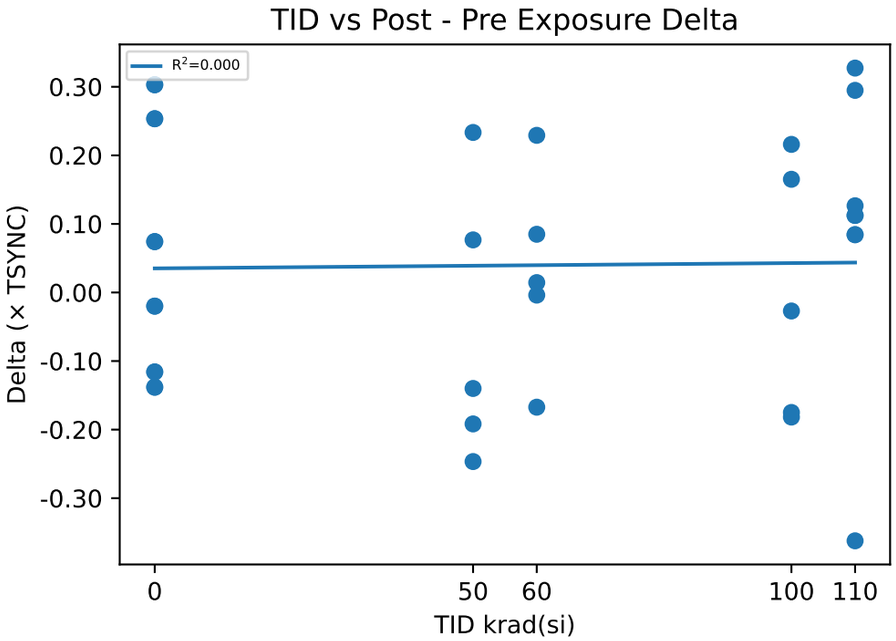
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5e-13	5e-13	0
2	0	CU2	5e-13	5e-13	0
3	0	CU3	5e-13	5e-13	0
11	50	Unbiased-50k	5e-13	5e-13	0
12	50	Unbiased-50k	5e-13	5e-13	0
13	50	Unbiased-50k	5e-13	5e-13	0
14	50	Unbiased-50k	5e-13	5e-13	0
16	50	Unbiased-50k	5e-13	5e-13	0
17	60	Biased-50k	5e-13	5e-13	0
18	60	Biased-50k	5e-13	5e-13	0
19	60	Biased-50k	5e-13	5e-13	0
20	60	Biased-50k	5e-13	5e-13	0
21	60	Biased-50k	5e-13	5e-13	0
24	100	Unbiased-100k	5e-13	5e-13	0
25	100	Unbiased-100k	5e-13	5e-13	0
26	100	Unbiased-100k	5e-13	5e-13	0
27	100	Unbiased-100k	5e-13	5e-13	0
28	100	Unbiased-100k	5e-13	5e-13	0
29	110	Biased-100k	5e-13	5e-13	0
30	110	Biased-100k	5e-13	5e-13	0
31	110	Biased-100k	5e-13	5e-13	0
32	110	Biased-100k	5e-13	5e-13	0
34	110	Biased-100k	5e-13	5e-13	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
50	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
60	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
100	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
110	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0

Device Test: 72.22 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW1/3/3/////1.8///@T_CLOCK_DET)





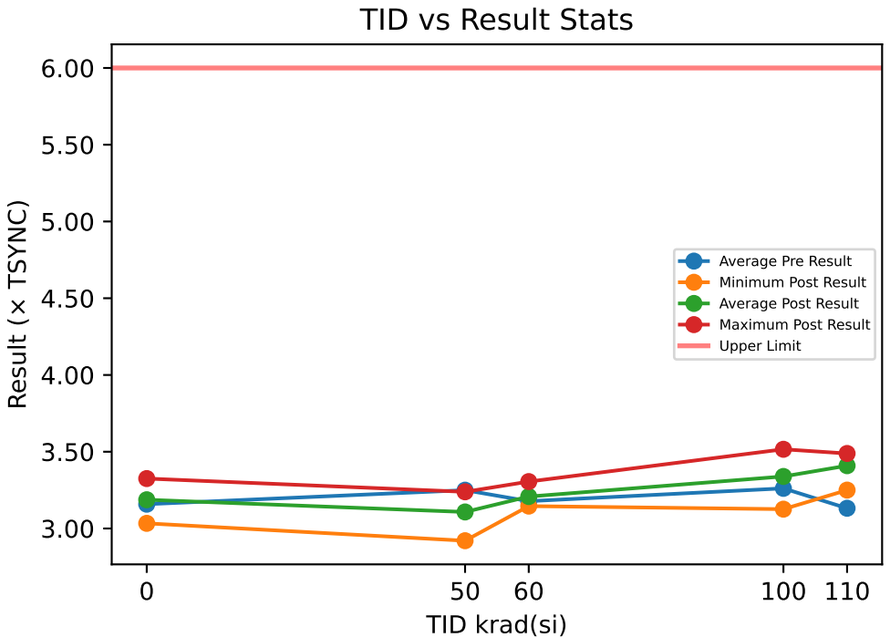
Test Results (Upper Limit = 6.0 (× TSYNC))

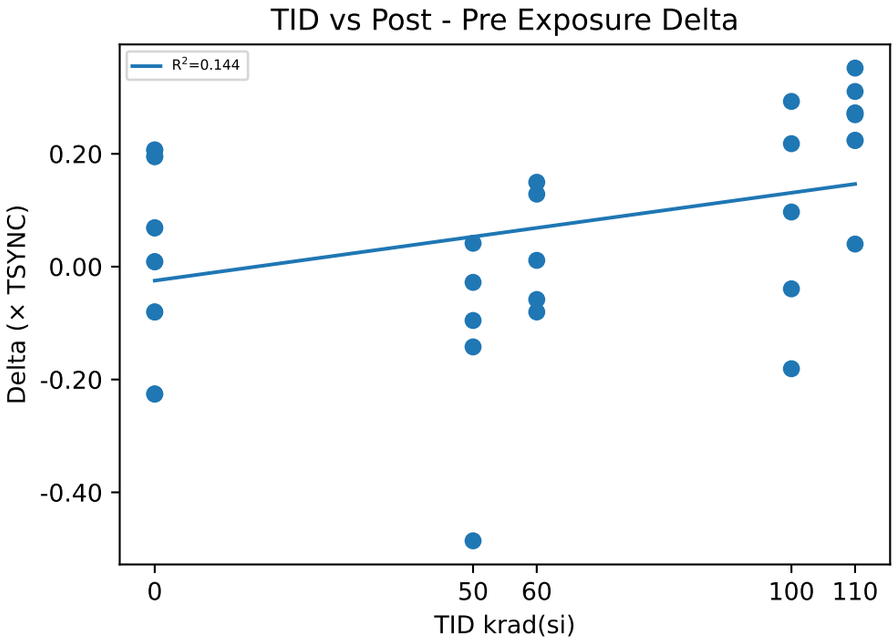
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.071	3.3244	0.2534
2	0	CU2	3.2819	3.1438	-0.1381
3	0	CU3	3.2936	3.3678	0.0742
11	50	Unbiased-50k	3.2307	3.0907	-0.14
12	50	Unbiased-50k	3.1296	3.2063	0.0767
13	50	Unbiased-50k	3.2303	3.0386	-0.1917
14	50	Unbiased-50k	3.3467	3.1001	-0.2466
16	50	Unbiased-50k	2.8462	3.0796	0.2334
17	60	Biased-50k	3.1547	3.3839	0.2292
18	60	Biased-50k	3.1981	3.1943	-0.0038
19	60	Biased-50k	3.0968	3.1112	0.0144
20	60	Biased-50k	3.1966	3.2815	0.0849
21	60	Biased-50k	3.3445	3.1772	-0.1673
24	100	Unbiased-100k	3.3473	3.3203	-0.027
25	100	Unbiased-100k	3.4029	3.2212	-0.1817
26	100	Unbiased-100k	3.1467	3.3118	0.1651
27	100	Unbiased-100k	3.1086	3.3246	0.216
28	100	Unbiased-100k	3.2376	3.0626	-0.175
29	110	Biased-100k	3.3165	3.443	0.1265
30	110	Biased-100k	2.9937	3.321	0.3273
31	110	Biased-100k	3.5012	3.139	-0.3622
32	110	Biased-100k	2.9868	3.2816	0.2948
34	110	Biased-100k	3.2196	3.332	0.1124

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.071	3.2155	3.2936	0.12528	3.1438	3.2787	3.3678	0.1188	-0.1381	0.063167	0.2534	0.19598
50	2.8462	3.1567	3.3467	0.18983	3.0386	3.1031	3.2063	0.062301	-0.2466	-0.05364	0.2334	0.20195
60	3.0968	3.1981	3.3445	0.091625	3.1112	3.2296	3.3839	0.10549	-0.1673	0.03148	0.2292	0.14405
100	3.1086	3.2486	3.4029	0.12615	3.0626	3.2481	3.3246	0.11209	-0.1817	-0.00052	0.216	0.18593
110	2.9868	3.2036	3.5012	0.21945	3.139	3.3033	3.443	0.10968	-0.3622	0.09976	0.3273	0.27572

Device Test: 72.23 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW2/3/3/////1.8///@T_CLOCK_DET)





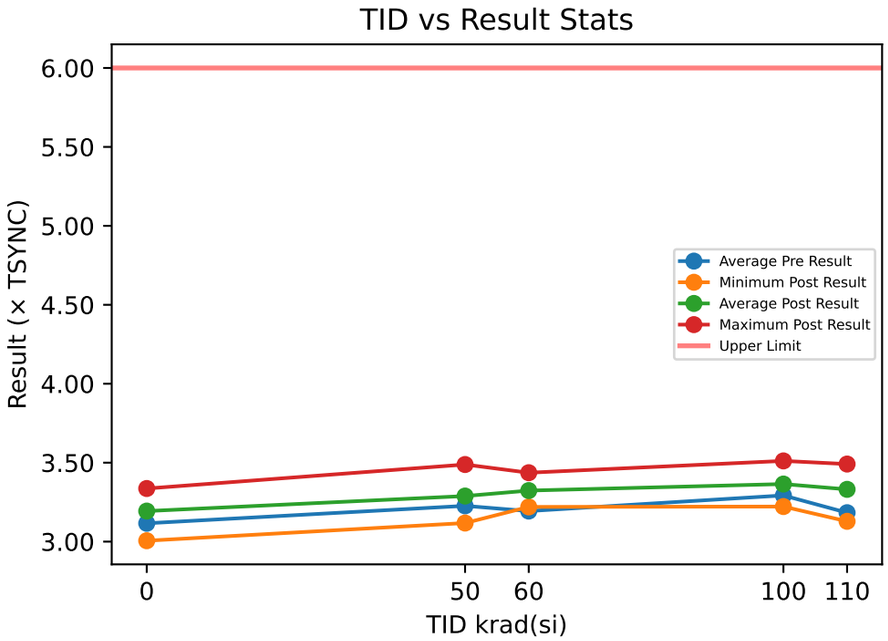
Test Results (Upper Limit = 6.0 (× TSYNC))

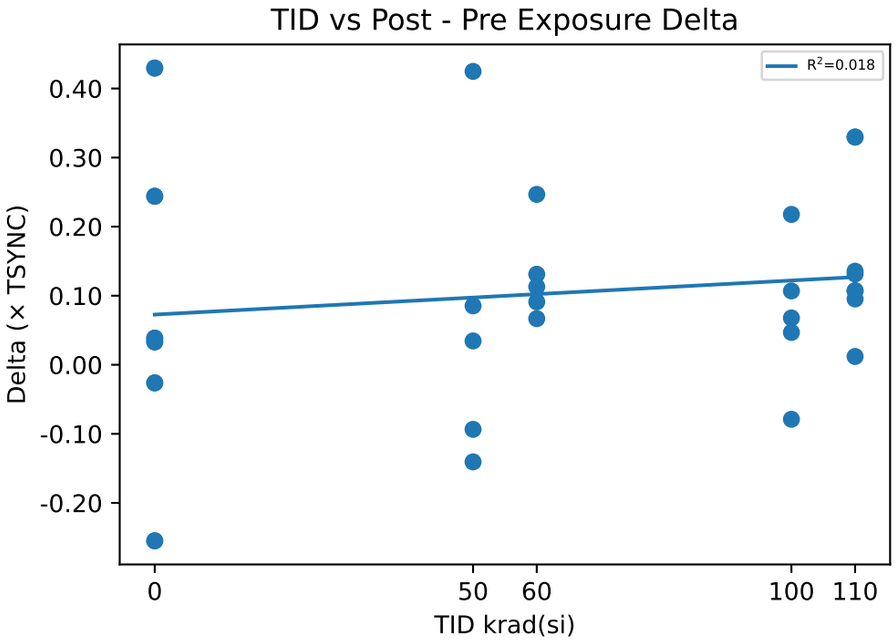
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.4055	3.3252	-0.0803
2	0	CU2	3.0446	3.2514	0.2068
3	0	CU3	3.0247	3.0335	0.0088
11	50	Unbiased-50k	3.287	3.1448	-0.1422
12	50	Unbiased-50k	3.3343	3.2389	-0.0954
13	50	Unbiased-50k	3.4062	2.9203	-0.4859
14	50	Unbiased-50k	3.1859	3.2274	0.0415
16	50	Unbiased-50k	3.0345	3.0067	-0.0278
17	60	Biased-50k	3.2945	3.2142	-0.0803
18	60	Biased-50k	3.204	3.1458	-0.0582
19	60	Biased-50k	3.1559	3.3055	0.1496
20	60	Biased-50k	3.1903	3.2015	0.0112
21	60	Biased-50k	3.0445	3.1731	0.1286
24	100	Unbiased-100k	3.4191	3.516	0.0969
25	100	Unbiased-100k	3.2155	3.4335	0.218
26	100	Unbiased-100k	3.368	3.3287	-0.0393
27	100	Unbiased-100k	3.3068	3.1259	-0.1809
28	100	Unbiased-100k	2.9975	3.2904	0.2929
29	110	Biased-100k	3.1413	3.4518	0.3105
30	110	Biased-100k	2.9808	3.2501	0.2693
31	110	Biased-100k	3.01	3.362	0.352
32	110	Biased-100k	3.3108	3.3509	0.0401
34	110	Biased-100k	3.2163	3.4886	0.2723

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.0247	3.1583	3.4055	0.21434	3.0335	3.2034	3.3252	0.15167	-0.0803	0.0451	0.2068	0.14695
50	3.0345	3.2496	3.4062	0.14441	2.9203	3.1076	3.2389	0.13985	-0.4859	-0.14196	0.0415	0.20442
60	3.0445	3.1778	3.2945	0.09043	3.1458	3.208	3.3055	0.060568	-0.0803	0.03018	0.1496	0.10527
100	2.9975	3.2614	3.4191	0.16586	3.1259	3.3389	3.516	0.14844	-0.1809	0.07752	0.2929	0.19166
110	2.9808	3.1318	3.3108	0.13866	3.2501	3.3807	3.4886	0.09353	0.0401	0.24884	0.352	0.12143

Device Test: 72.24 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW3/3/3/////1.8///@T_CLOCK_DET)





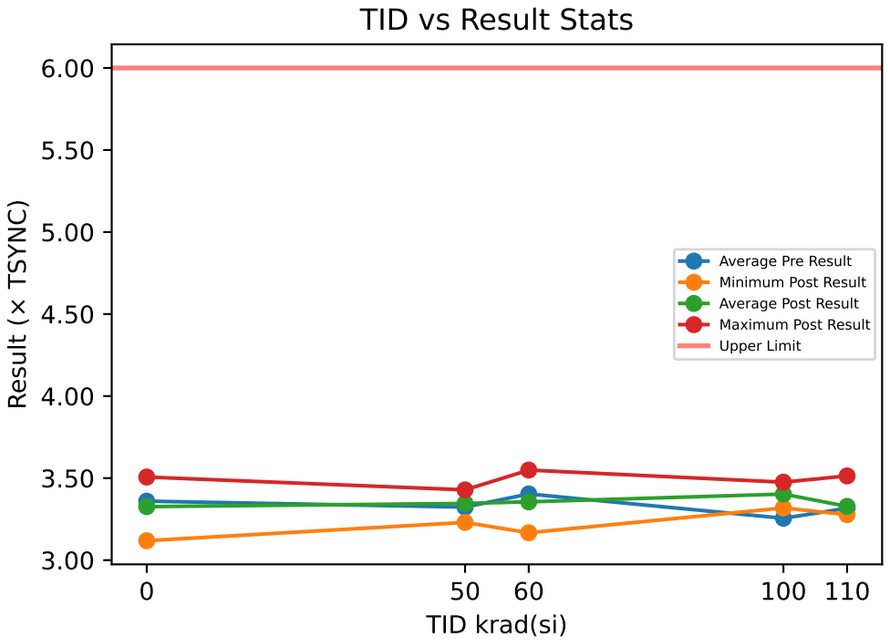
Test Results (Upper Limit = 6.0 (× TSYNC))

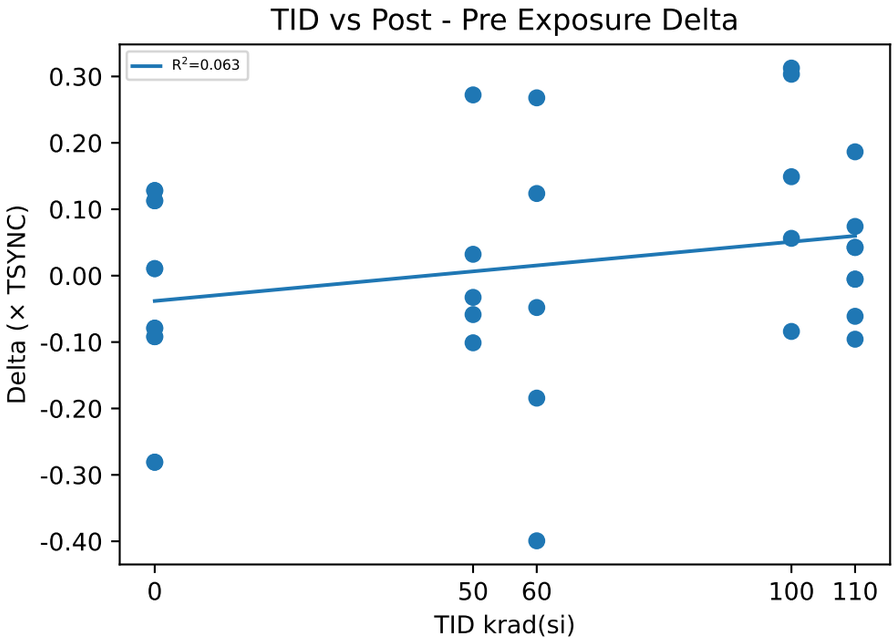
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.2606	3.0057	-0.2549
2	0	CU2	2.9068	3.1508	0.244
3	0	CU3	3.1808	3.2139	0.0331
11	50	Unbiased-50k	3.2759	3.3612	0.0853
12	50	Unbiased-50k	3.2112	3.1177	-0.0935
13	50	Unbiased-50k	3.2898	3.3243	0.0345
14	50	Unbiased-50k	3.2924	3.1518	-0.1406
16	50	Unbiased-50k	3.0635	3.4883	0.4248
17	60	Biased-50k	3.1251	3.3718	0.2467
18	60	Biased-50k	3.2072	3.2983	0.0911
19	60	Biased-50k	3.3053	3.4364	0.1311
20	60	Biased-50k	3.153	3.2198	0.0668
21	60	Biased-50k	3.177	3.29	0.113
24	100	Unbiased-100k	3.4043	3.5112	0.1069
25	100	Unbiased-100k	3.2775	3.3243	0.0468
26	100	Unbiased-100k	3.3017	3.3695	0.0678
27	100	Unbiased-100k	3.1787	3.3964	0.2177
28	100	Unbiased-100k	3.301	3.2221	-0.0789
29	110	Biased-100k	3.1906	3.2026	0.012
30	110	Biased-100k	3.0333	3.1286	0.0953
31	110	Biased-100k	3.2127	3.3442	0.1315
32	110	Biased-100k	3.3174	3.4529	0.1355
34	110	Biased-100k	3.1616	3.4913	0.3297

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.9068	3.1161	3.2606	0.18557	3.0057	3.1235	3.2139	0.10676	-0.2549	0.0074	0.244	0.25044
50	3.0635	3.2266	3.2924	0.096945	3.1177	3.2887	3.4883	0.15358	-0.1406	0.0621	0.4248	0.22257
60	3.1251	3.1935	3.3053	0.069423	3.2198	3.3233	3.4364	0.083051	0.0668	0.12974	0.2467	0.069671
100	3.1787	3.2926	3.4043	0.080361	3.2221	3.3647	3.5112	0.10542	-0.0789	0.07206	0.2177	0.10709
110	3.0333	3.1831	3.3174	0.10231	3.1286	3.3239	3.4913	0.15647	0.012	0.1408	0.3297	0.11668

Device Test: 72.25 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW4/3/3/////1.8///@T_CLOCK_DET)





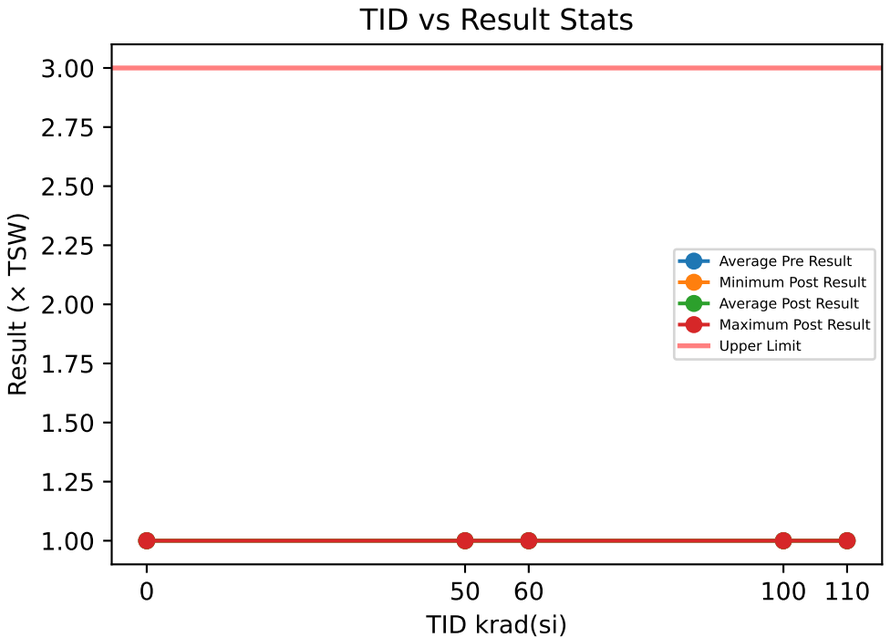
Test Results (Upper Limit = 6.0 (× TSYNC))

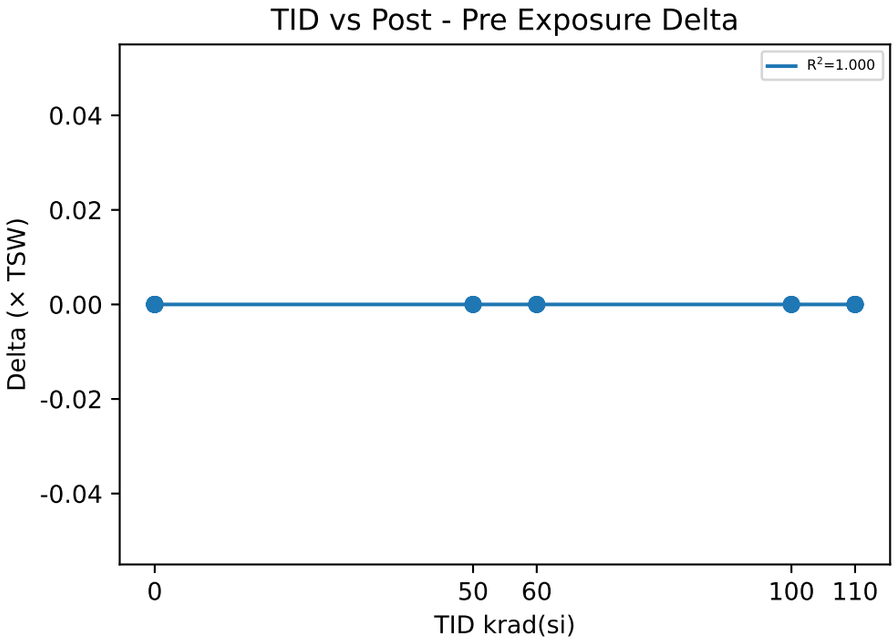
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.3993	3.3074	-0.0919
2	0	CU2	3.2855	3.4136	0.1281
3	0	CU3	3.3938	3.3147	-0.0791
11	50	Unbiased-50k	3.331	3.2299	-0.1011
12	50	Unbiased-50k	3.3962	3.4284	0.0322
13	50	Unbiased-50k	3.3666	3.308	-0.0586
14	50	Unbiased-50k	3.4103	3.3776	-0.0327
16	50	Unbiased-50k	3.1123	3.3845	0.2722
17	60	Biased-50k	3.2707	3.3944	0.1237
18	60	Biased-50k	3.3514	3.167	-0.1844
19	60	Biased-50k	3.2812	3.549	0.2678
20	60	Biased-50k	3.4275	3.3795	-0.048
21	60	Biased-50k	3.6865	3.2872	-0.3993
24	100	Unbiased-100k	3.1325	3.4451	0.3126
25	100	Unbiased-100k	3.4021	3.3181	-0.084
26	100	Unbiased-100k	3.2787	3.4277	0.149
27	100	Unbiased-100k	3.0446	3.3479	0.3033
28	100	Unbiased-100k	3.419	3.4752	0.0562
29	110	Biased-100k	3.3269	3.5134	0.1865
30	110	Biased-100k	3.3729	3.2772	-0.0957
31	110	Biased-100k	3.3545	3.2933	-0.0612
32	110	Biased-100k	3.2398	3.3139	0.0741
34	110	Biased-100k	3.2872	3.3297	0.0425

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.2855	3.3595	3.3993	0.064174	3.3074	3.3452	3.4136	0.05932	-0.0919	-0.0143	0.1281	0.12349
50	3.1123	3.3233	3.4103	0.1218	3.2299	3.3457	3.4284	0.077771	-0.1011	0.0224	0.2722	0.14777
60	3.2707	3.4035	3.6865	0.17027	3.167	3.3554	3.549	0.14118	-0.3993	-0.04804	0.2678	0.2604
100	3.0446	3.2554	3.419	0.1646	3.3181	3.4028	3.4752	0.066782	-0.084	0.14742	0.3126	0.16842
110	3.2398	3.3163	3.3729	0.053559	3.2772	3.3455	3.5134	0.095954	-0.0957	0.02924	0.1865	0.11259

Device Test: 72.28 T_CLOCK_DET_EXT(EXT_CLOCK|IntToExtClkDetect/GNG_SW1/3/3/////1.8///@T_CLOCK_DET_EXT)





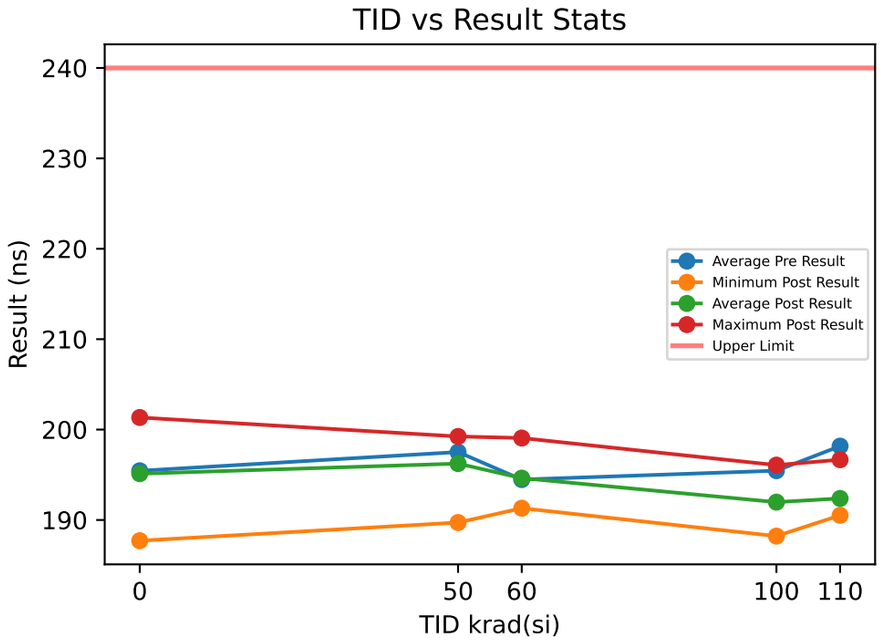
Test Results (Upper Limit = 3.0 (× TSW))

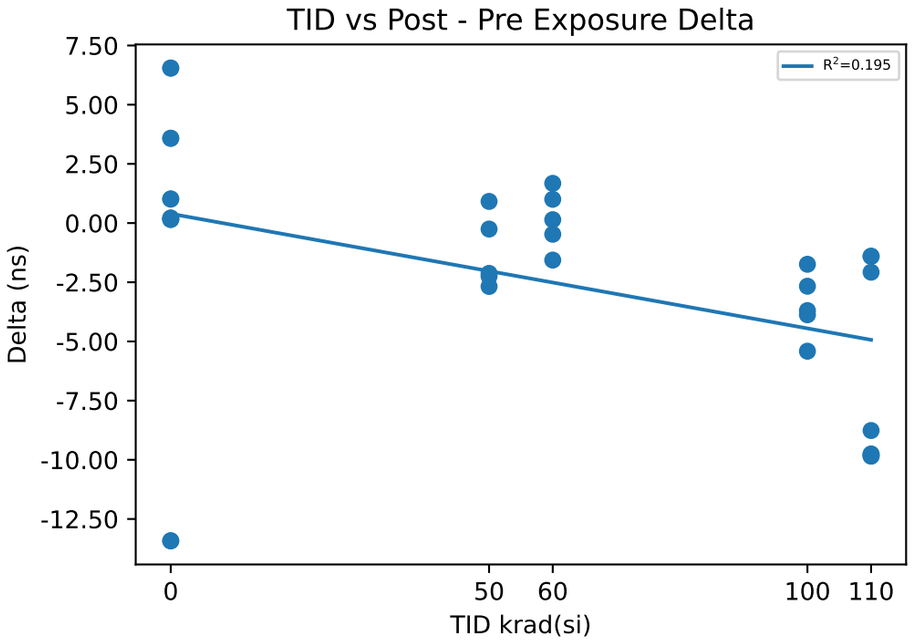
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1	1	0
2	0	CU2	1	1	0
3	0	CU3	1	1	0
11	50	Unbiased-50k	1	1	0
12	50	Unbiased-50k	1	1	0
13	50	Unbiased-50k	1	1	0
14	50	Unbiased-50k	1	1	0
16	50	Unbiased-50k	1	1	0
17	60	Biased-50k	1	1	0
18	60	Biased-50k	1	1	0
19	60	Biased-50k	1	1	0
20	60	Biased-50k	1	1	0
21	60	Biased-50k	1	1	0
24	100	Unbiased-100k	1	1	0
25	100	Unbiased-100k	1	1	0
26	100	Unbiased-100k	1	1	0
27	100	Unbiased-100k	1	1	0
28	100	Unbiased-100k	1	1	0
29	110	Biased-100k	1	1	0
30	110	Biased-100k	1	1	0
31	110	Biased-100k	1	1	0
32	110	Biased-100k	1	1	0
34	110	Biased-100k	1	1	0

Test Statistics (× TSW)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1	1	1	0	1	1	1	0	0	0	0	0
50	1	1	1	0	1	1	1	0	0	0	0	0
60	1	1	1	0	1	1	1	0	0	0	0	0
100	1	1	1	0	1	1	1	0	0	0	0	0
110	1	1	1	0	1	1	1	0	0	0	0	0

evice Test: 73.1 SYNC_SW_DELAY_VIN_5V(EXT_CLOCK|Delay/SYNC_to_SW1/5/5/////1.8///@SYNC_SW_DELAY_VIN_5





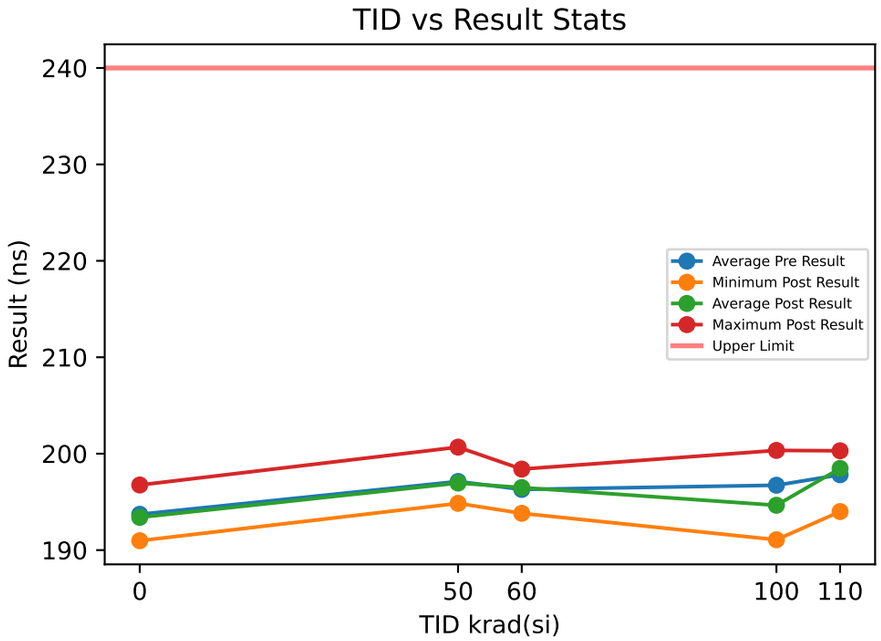
Test Results (Upper Limit = 240.0 (ns))

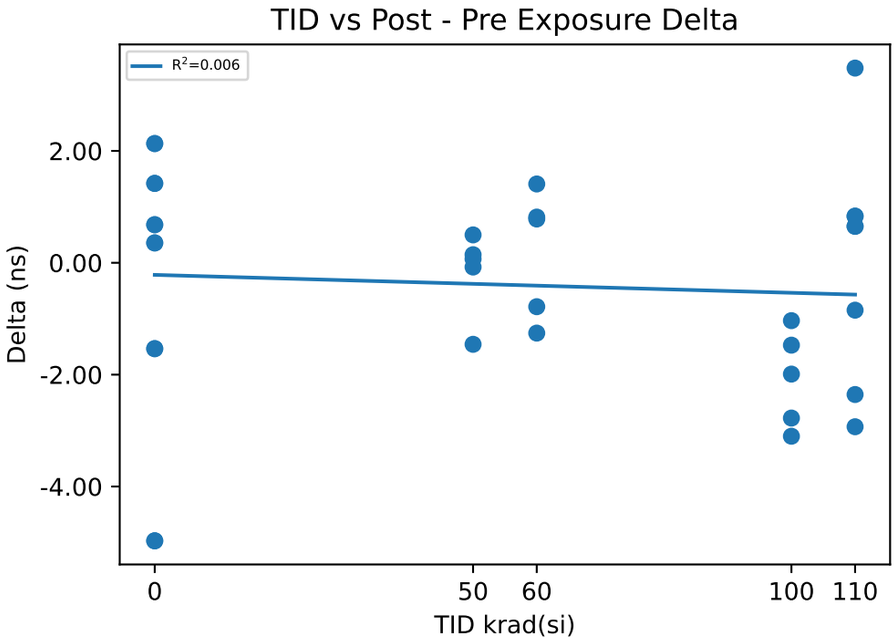
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	189.98	190.13	0.1544
2	0	CU2	201.13	201.34	0.2089
3	0	CU3	195.21	196.23	1.0155
11	50	Unbiased-50k	199.88	197.2	-2.6779
12	50	Unbiased-50k	197.17	198.08	0.9143
13	50	Unbiased-50k	201.36	199.24	-2.1257
14	50	Unbiased-50k	189.97	189.72	-0.2529
16	50	Unbiased-50k	199.2	196.95	-2.2483
17	60	Biased-50k	192.87	191.3	-1.5639
18	60	Biased-50k	192.71	192.85	0.1419
19	60	Biased-50k	194.63	194.16	-0.472
20	60	Biased-50k	194.1	195.78	1.6765
21	60	Biased-50k	198.06	199.07	1.0043
24	100	Unbiased-100k	197.19	193.5	-3.6978
25	100	Unbiased-100k	197.81	196.07	-1.7405
26	100	Unbiased-100k	196.45	193.79	-2.6682
27	100	Unbiased-100k	193.71	188.3	-5.4124
28	100	Unbiased-100k	192.09	188.22	-3.8747
29	110	Biased-100k	194.89	193.49	-1.4012
30	110	Biased-100k	198.07	196.67	-1.4072
31	110	Biased-100k	194.46	192.38	-2.0757
32	110	Biased-100k	203.07	194.31	-8.7635
34	110	Biased-100k	200.36	190.59	-9.7605

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.98	195.44	201.13	5.5782	190.13	195.9	201.34	5.609	0.1544	0.4596	1.0155	0.48219
50	189.97	197.52	201.36	4.4804	189.72	196.24	199.24	3.7538	-2.6779	-1.2781	0.9143	1.5392
60	192.71	194.47	198.06	2.1647	191.3	194.63	199.07	2.9776	-1.5639	0.15736	1.6765	1.2633
100	192.09	195.45	197.81	2.4452	188.22	191.97	196.07	3.5349	-5.4124	-3.4787	-1.7405	1.3804
110	194.46	198.17	203.07	3.6512	190.59	193.49	196.67	2.2564	-9.7605	-4.6816	-1.4012	4.2051

evice Test: 73.2 SYNC_SW_DELAY_VIN_5V(EXT_CLOCK|Delay/SYNC_to_SW2/5/5/////1.8///@SYNC_SW_DELAY_VIN_5





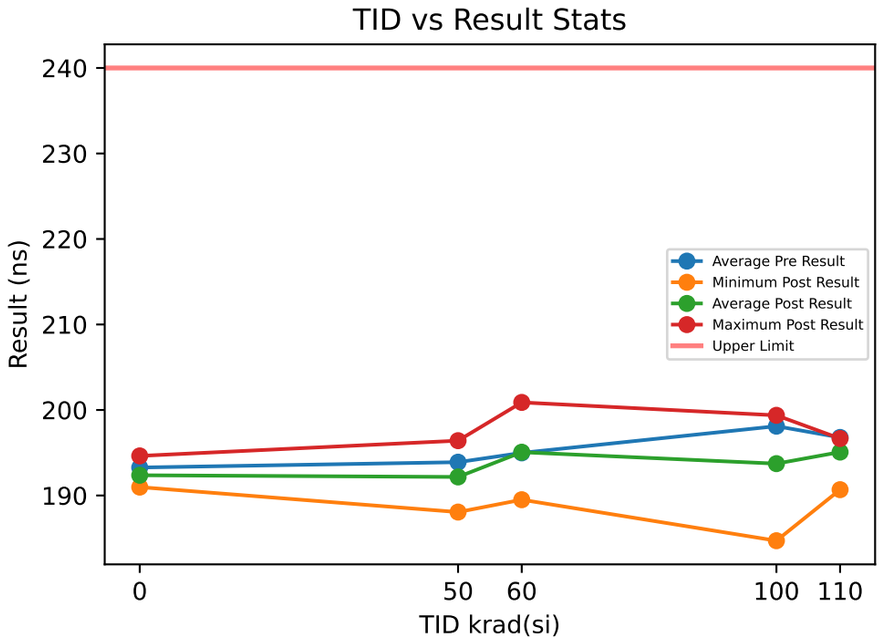
Test Results (Upper Limit = 240.0 (ns))

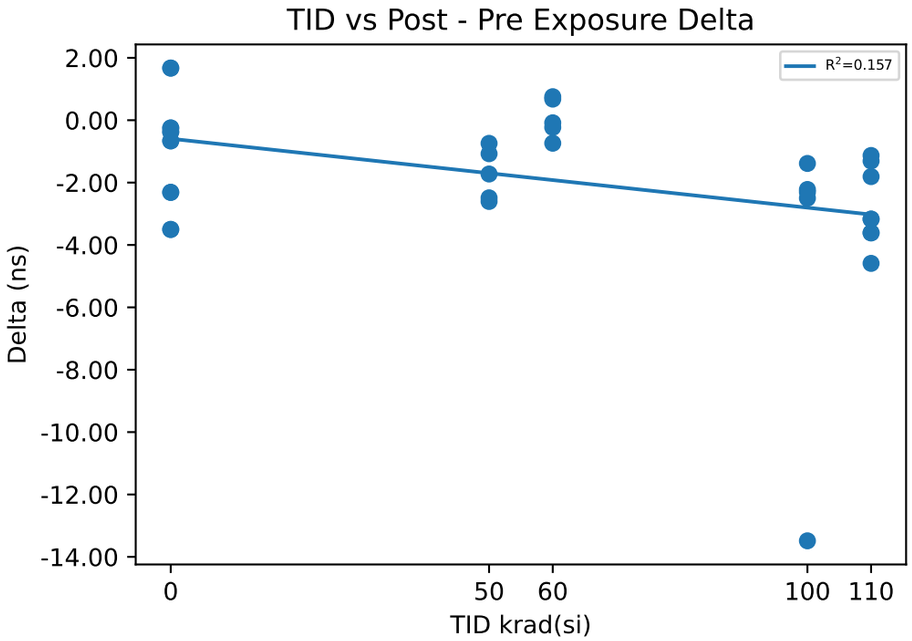
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	196.07	196.75	0.6805
2	0	CU2	192.56	192.92	0.3551
3	0	CU3	192.51	193.93	1.4191
11	50	Unbiased-50k	200.53	200.68	0.1444
12	50	Unbiased-50k	196.43	196.92	0.4986
13	50	Unbiased-50k	198.52	197.06	-1.4577
14	50	Unbiased-50k	195.19	195.26	0.0677
16	50	Unbiased-50k	194.92	194.85	-0.0761
17	60	Biased-50k	196.68	195.42	-1.2572
18	60	Biased-50k	196.29	197.7	1.4087
19	60	Biased-50k	199.19	198.4	-0.7851
20	60	Biased-50k	193	193.81	0.8168
21	60	Biased-50k	196.31	197.09	0.7825
24	100	Unbiased-100k	196.14	194.15	-1.99
25	100	Unbiased-100k	201.37	200.34	-1.0345
26	100	Unbiased-100k	194.17	191.07	-3.1009
27	100	Unbiased-100k	198.04	195.26	-2.7761
28	100	Unbiased-100k	193.9	192.43	-1.4727
29	110	Biased-100k	196.93	194	-2.9314
30	110	Biased-100k	195.13	198.61	3.4809
31	110	Biased-100k	201.14	200.3	-0.8473
32	110	Biased-100k	196.39	194.04	-2.3552
34	110	Biased-100k	199.47	200.3	0.833

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.51	193.71	196.07	2.0406	192.92	194.53	196.75	1.9862	0.3551	0.81823	1.4191	0.54521
50	194.92	197.12	200.53	2.3788	194.85	196.95	200.68	2.3021	-1.4577	-0.16462	0.4986	0.7532
60	193	196.29	199.19	2.2005	193.81	196.48	198.4	1.8557	-1.2572	0.19314	1.4087	1.1483
100	193.9	196.73	201.37	3.0878	191.07	194.65	200.34	3.5603	-3.1009	-2.0748	-1.0345	0.86554
110	195.13	197.81	201.14	2.4397	194	197.45	200.3	3.2068	-2.9314	-0.364	3.4809	2.5984

evice Test: 73.3 SYNC_SW_DELAY_VIN_5V(EXT_CLOCK|Delay/SYNC_to_SW3/5/5/////1.8///@SYNC_SW_DELAY_VIN_5





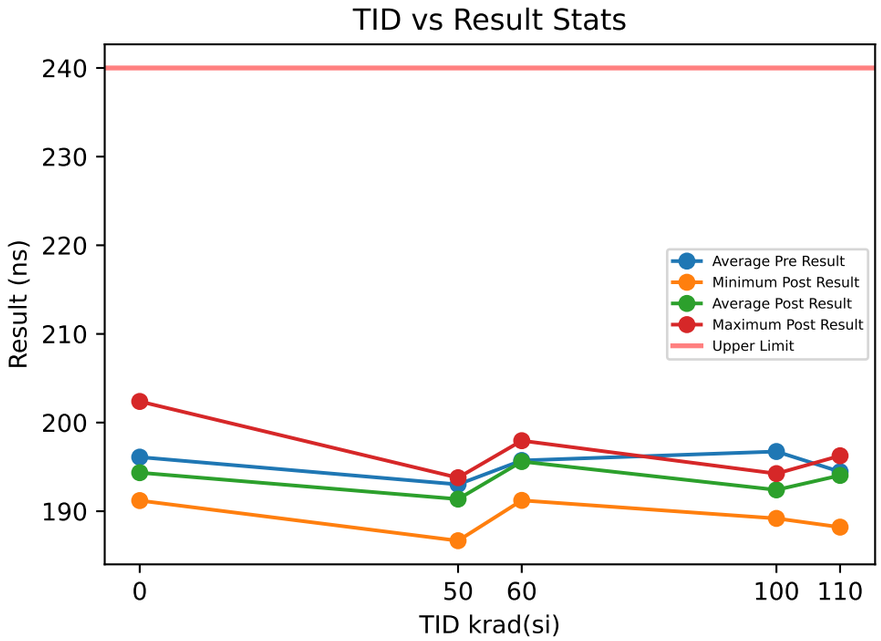
Test Results (Upper Limit = 240.0 (ns))

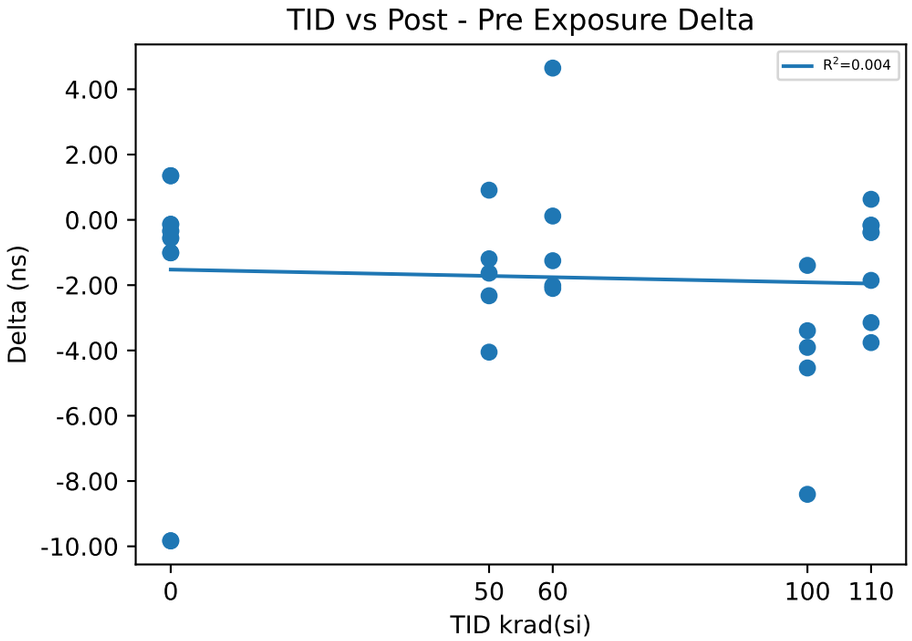
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	193.58	192.92	-0.6623
2	0	CU2	195.01	194.63	-0.377
3	0	CU3	191.23	190.98	-0.2494
11	50	Unbiased-50k	193.19	190.7	-2.4889
12	50	Unbiased-50k	197.48	196.41	-1.0746
13	50	Unbiased-50k	190.66	188.06	-2.6044
14	50	Unbiased-50k	193.7	191.97	-1.7248
16	50	Unbiased-50k	194.45	193.71	-0.7422
17	60	Biased-50k	189.93	190.69	0.7538
18	60	Biased-50k	198.34	199.01	0.677
19	60	Biased-50k	190.24	189.5	-0.738
20	60	Biased-50k	195.3	195.22	-0.0827
21	60	Biased-50k	201.12	200.89	-0.2298
24	100	Unbiased-100k	198.2	184.71	-13.486
25	100	Unbiased-100k	193.38	190.88	-2.5003
26	100	Unbiased-100k	199.15	196.85	-2.3057
27	100	Unbiased-100k	201.6	199.38	-2.2212
28	100	Unbiased-100k	198.2	196.81	-1.3867
29	110	Biased-100k	197.79	196.66	-1.1313
30	110	Biased-100k	193.93	192.13	-1.8079
31	110	Biased-100k	197.26	195.95	-1.3081
32	110	Biased-100k	195.27	190.68	-4.5903
34	110	Biased-100k	199.69	196.08	-3.6113

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	191.23	193.27	195.01	1.9075	190.98	192.84	194.63	1.8262	-0.6623	-0.42957	-0.2494	0.21141
50	190.66	193.9	197.48	2.4582	188.06	192.17	196.41	3.1401	-2.6044	-1.727	-0.7422	0.82852
60	189.93	194.99	201.12	4.9225	189.5	195.06	200.89	4.9895	-0.738	0.07606	0.7538	0.63283
100	193.38	198.1	201.6	2.9847	184.71	193.72	199.38	5.9281	-13.486	-4.3799	-1.3867	5.108
110	193.93	196.79	199.69	2.2422	190.68	194.3	196.66	2.7058	-4.5903	-2.4898	-1.1313	1.5311

evice Test: 73.4 SYNC_SW_DELAY_VIN_5V(EXT_CLOCK|Delay/SYNC_to_SW4/5/5/////1.8///@SYNC_SW_DELAY_VIN_5





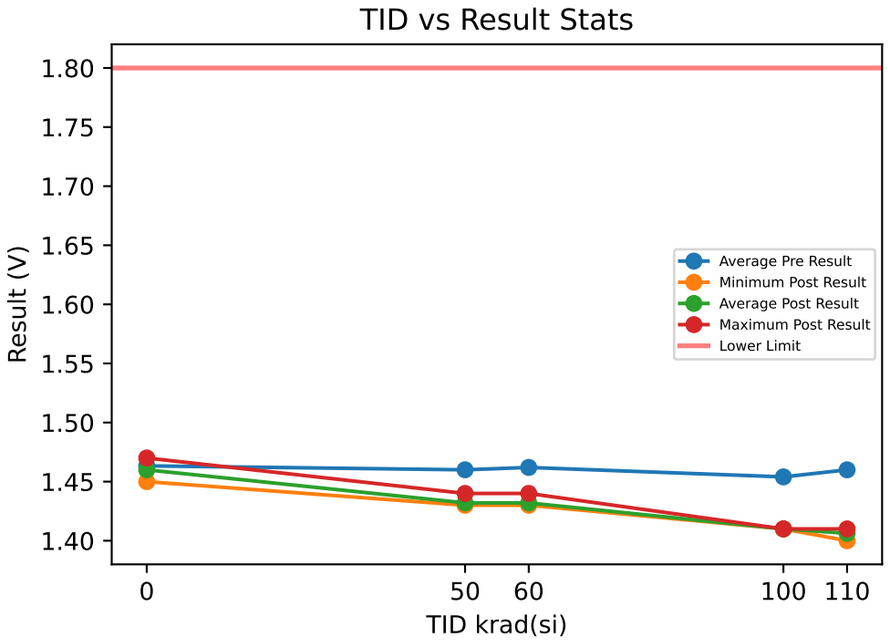
Test Results (Upper Limit = 240.0 (ns))

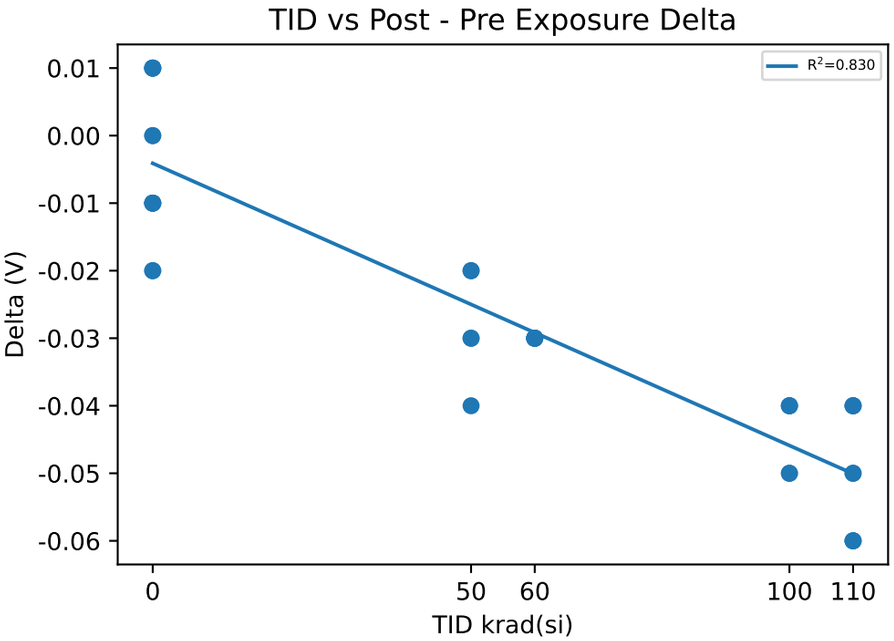
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	194.44	193.88	-0.5598
2	0	CU2	192.84	192.5	-0.3435
3	0	CU3	201.03	202.38	1.3514
11	50	Unbiased-50k	194.24	193.05	-1.1924
12	50	Unbiased-50k	194.43	192.11	-2.3254
13	50	Unbiased-50k	197.83	193.78	-4.052
14	50	Unbiased-50k	190.31	191.22	0.9092
16	50	Unbiased-50k	188.3	186.67	-1.6322
17	60	Biased-50k	193.24	191.22	-2.0162
18	60	Biased-50k	197.84	197.96	0.1172
19	60	Biased-50k	190.61	195.26	4.6489
20	60	Biased-50k	199.49	197.39	-2.1012
21	60	Biased-50k	197.43	196.18	-1.2517
24	100	Unbiased-100k	196.08	192.18	-3.9059
25	100	Unbiased-100k	195.64	194.24	-1.3948
26	100	Unbiased-100k	193.72	189.19	-4.5364
27	100	Unbiased-100k	200.76	192.35	-8.4071
28	100	Unbiased-100k	197.47	194.08	-3.3956
29	110	Biased-100k	195.3	192.15	-3.1477
30	110	Biased-100k	190.06	188.2	-1.8539
31	110	Biased-100k	194.86	191.1	-3.7595
32	110	Biased-100k	195.63	196.25	0.6296
34	110	Biased-100k	196.42	196.04	-0.384

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	192.84	196.1	201.03	4.3427	192.5	196.25	202.38	5.3543	-0.5598	0.14937	1.3514	1.0466
50	188.3	193.02	197.83	3.7491	186.67	191.37	193.78	2.7954	-4.052	-1.6586	0.9092	1.8017
60	190.61	195.72	199.49	3.6725	191.22	195.6	197.96	2.6643	-2.1012	-0.1206	4.6489	2.8107
100	193.72	196.73	200.76	2.6172	189.19	192.41	194.24	2.0354	-8.4071	-4.328	-1.3948	2.5658
110	190.06	194.45	196.42	2.5227	188.2	192.75	196.25	3.4221	-3.7595	-1.7031	0.6296	1.8385

Device Test: 73.5 SYNC_SW_VIH_VIN_5V(EXT_CLOCK|VIH/SYNC/5/5/////1.8///@SYNC_SW_VIH_VIN_5V)





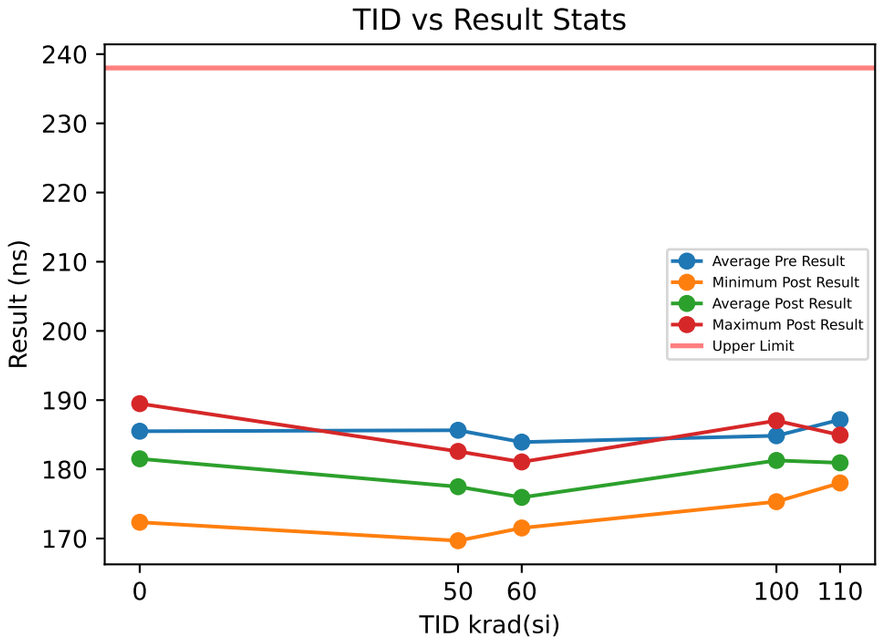
Test Results (Lower Limit = 1.8 (V))

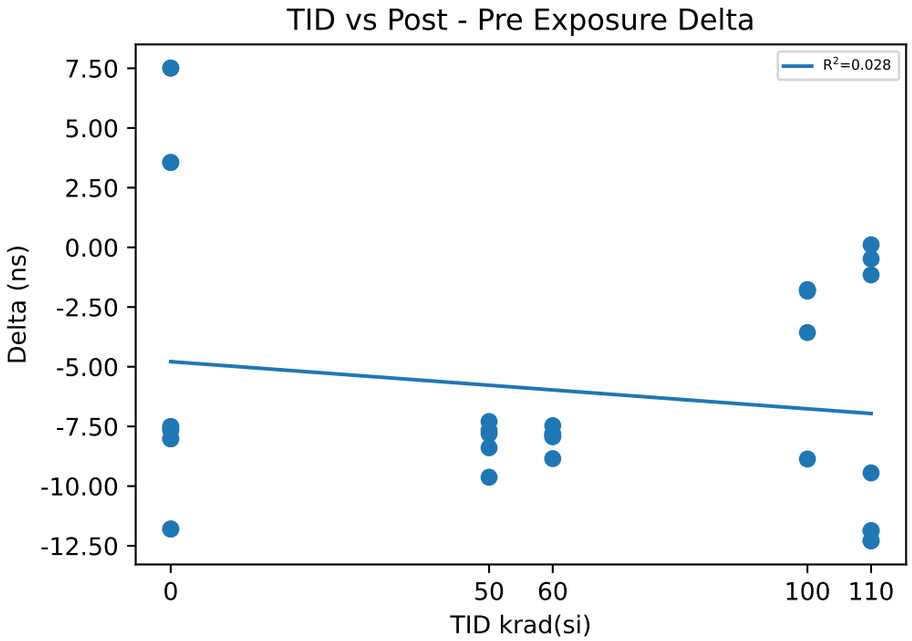
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.47	1.46	-0.01
2	0	CU2	1.46	1.47	0.01
3	0	CU3	1.46	1.45	-0.01
11	50	Unbiased-50k	1.45	1.43	-0.02
12	50	Unbiased-50k	1.46	1.43	-0.03
13	50	Unbiased-50k	1.46	1.43	-0.03
14	50	Unbiased-50k	1.46	1.44	-0.02
16	50	Unbiased-50k	1.47	1.43	-0.04
17	60	Biased-50k	1.46	1.43	-0.03
18	60	Biased-50k	1.47	1.44	-0.03
19	60	Biased-50k	1.46	1.43	-0.03
20	60	Biased-50k	1.46	1.43	-0.03
21	60	Biased-50k	1.46	1.43	-0.03
24	100	Unbiased-100k	1.45	1.41	-0.04
25	100	Unbiased-100k	1.45	1.41	-0.04
26	100	Unbiased-100k	1.46	1.41	-0.05
27	100	Unbiased-100k	1.46	1.41	-0.05
28	100	Unbiased-100k	1.45	1.41	-0.04
29	110	Biased-100k	1.47	1.41	-0.06
30	110	Biased-100k	1.46	1.4	-0.06
31	110	Biased-100k	1.45	1.41	-0.04
32	110	Biased-100k	1.47	1.41	-0.06
34	110	Biased-100k	1.45	1.4	-0.05

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.46	1.4633	1.47	0.0057735	1.45	1.46	1.47	0.01	-0.01	-0.0033333	0.01	0.011547
50	1.45	1.46	1.47	0.0070711	1.43	1.432	1.44	0.0044721	-0.04	-0.028	-0.02	0.0083666
60	1.46	1.462	1.47	0.0044721	1.43	1.432	1.44	0.0044721	-0.03	-0.03	-0.03	0
100	1.45	1.454	1.46	0.0054772	1.41	1.41	1.41	0	-0.05	-0.044	-0.04	0.0054772
110	1.45	1.46	1.47	0.01	1.4	1.406	1.41	0.0054772	-0.06	-0.054	-0.04	0.0089443

vice Test: 74.13 SYNC_SW_DELAY_VIN_7V(EXT_CLOCK|Delay/SYNC_to_SW1/7/7/////1.8///@SYNC_SW_DELAY_VIN_7





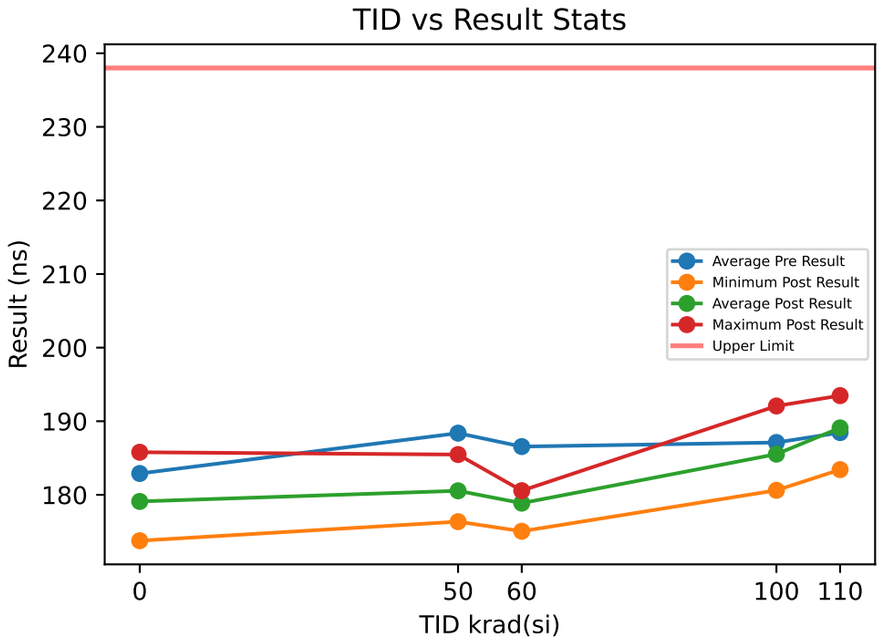
Test Results (Upper Limit = 238.0 (ns))

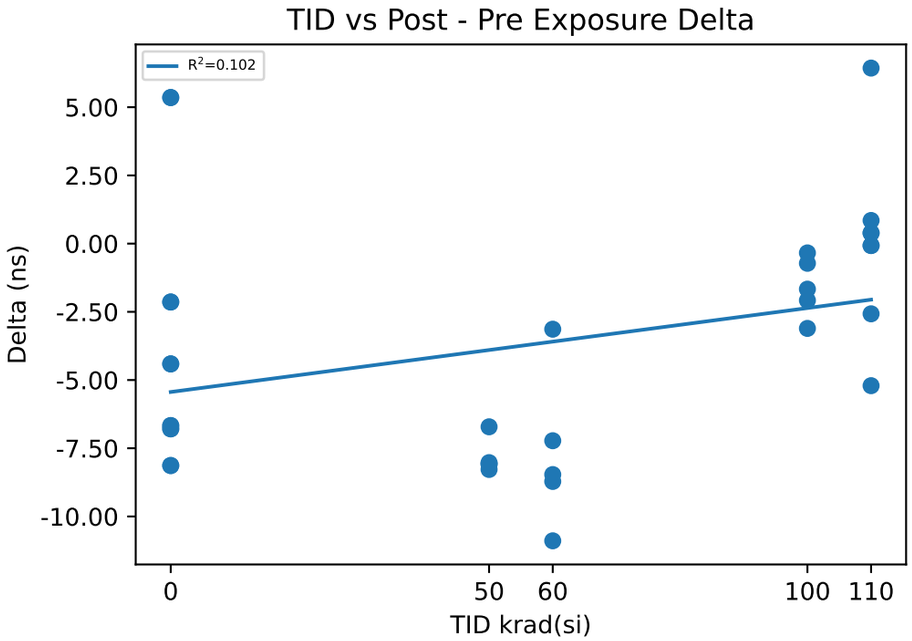
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	180	172.35	-7.6526
2	0	CU2	190.57	183.07	-7.5052
3	0	CU3	185.94	177.92	-8.0177
11	50	Unbiased-50k	186.8	178.41	-8.3946
12	50	Unbiased-50k	187.91	180.1	-7.8078
13	50	Unbiased-50k	190.25	182.59	-7.6622
14	50	Unbiased-50k	176.97	169.68	-7.294
16	50	Unbiased-50k	186.28	176.65	-9.6278
17	60	Biased-50k	179.46	171.52	-7.9348
18	60	Biased-50k	180.91	173.03	-7.8812
19	60	Biased-50k	183.27	175.8	-7.4672
20	60	Biased-50k	187.15	178.3	-8.848
21	60	Biased-50k	188.87	181.07	-7.7994
24	100	Unbiased-100k	187.75	185.98	-1.7687
25	100	Unbiased-100k	188.83	187.03	-1.8011
26	100	Unbiased-100k	183.86	182.03	-1.8334
27	100	Unbiased-100k	184.18	175.32	-8.8635
28	100	Unbiased-100k	179.63	176.06	-3.5667
29	110	Biased-100k	183.82	183.34	-0.4821
30	110	Biased-100k	185.87	184.72	-1.1539
31	110	Biased-100k	181.44	181.55	0.1083
32	110	Biased-100k	194.4	184.95	-9.4461
34	110	Biased-100k	190.32	178.45	-11.867

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	180	185.5	190.57	5.2993	172.35	177.78	183.07	5.3611	-8.0177	-7.7252	-7.5052	0.26384
50	176.97	185.64	190.25	5.0806	169.68	177.49	182.59	4.882	-9.6278	-8.1573	-7.294	0.91258
60	179.46	183.93	188.87	4.0082	171.52	175.95	181.07	3.8678	-8.848	-7.9861	-7.4672	0.51493
100	179.63	184.85	188.83	3.6393	175.32	181.28	187.03	5.4428	-8.8635	-3.5667	-1.7687	3.0582
110	181.44	187.17	194.4	5.1927	178.45	182.6	184.95	2.6864	-11.867	-4.5681	0.1083	5.641

vice Test: 74.14 SYNC_SW_DELAY_VIN_7V(EXT_CLOCK|Delay/SYNC_to_SW2/7/7/////1.8///@SYNC_SW_DELAY_VIN_7





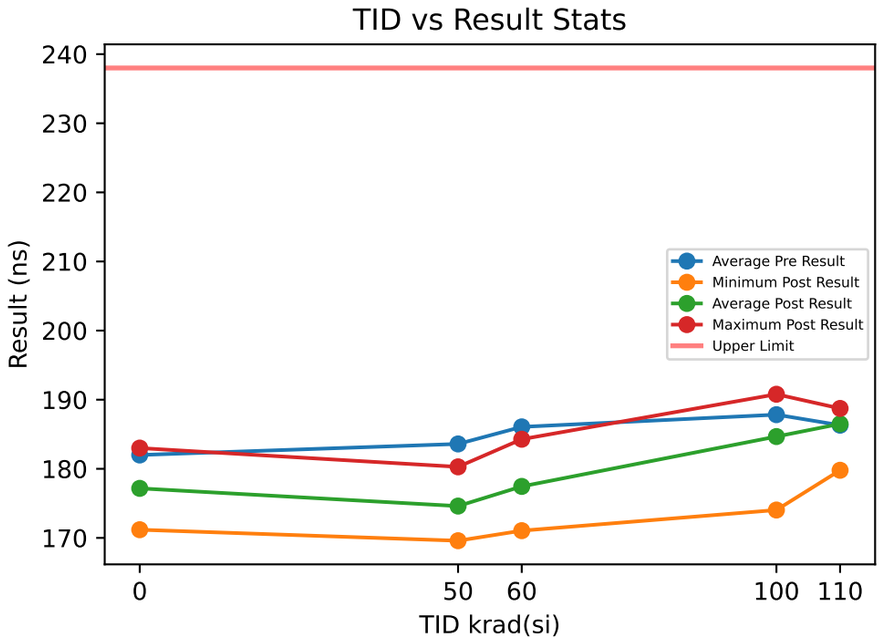
Test Results (Upper Limit = 238.0 (ns))

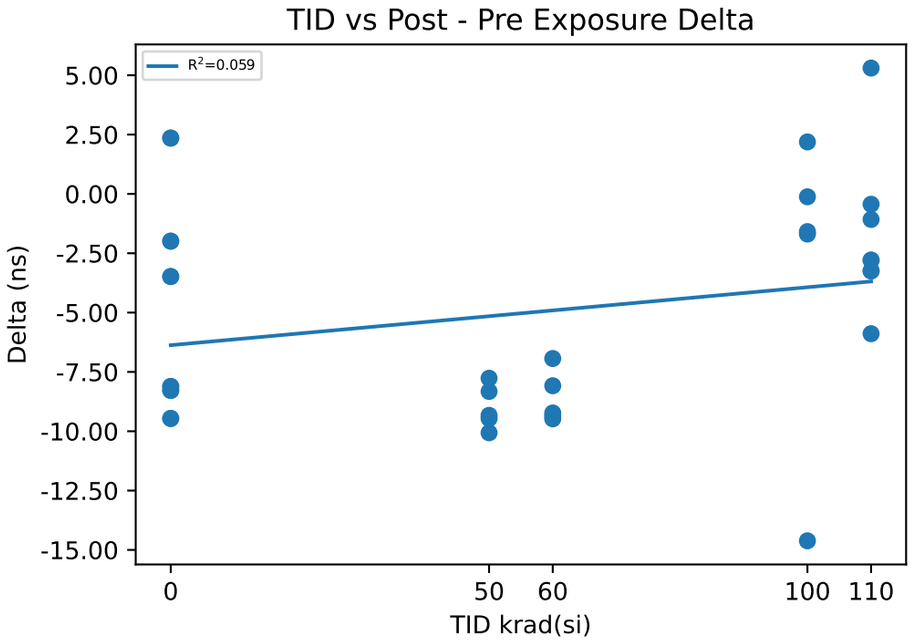
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	185.98	179.19	-6.7887
2	0	CU2	180.43	173.76	-6.6689
3	0	CU3	182.28	174.15	-8.1335
11	50	Unbiased-50k	192.19	185.47	-6.7138
12	50	Unbiased-50k	188.86	180.58	-8.2772
13	50	Unbiased-50k	189.56	181.47	-8.0909
14	50	Unbiased-50k	186.88	178.86	-8.027
16	50	Unbiased-50k	184.42	176.35	-8.0688
17	60	Biased-50k	188.22	179.51	-8.7166
18	60	Biased-50k	186.52	179.3	-7.2244
19	60	Biased-50k	190.82	179.93	-10.893
20	60	Biased-50k	183.51	175.05	-8.4647
21	60	Biased-50k	183.7	180.56	-3.1365
24	100	Unbiased-100k	186.25	184.17	-2.0797
25	100	Unbiased-100k	192.41	192.07	-0.3404
26	100	Unbiased-100k	182.28	180.61	-1.6684
27	100	Unbiased-100k	190.26	187.16	-3.1079
28	100	Unbiased-100k	184.34	183.62	-0.7212
29	110	Biased-100k	187.48	184.91	-2.573
30	110	Biased-100k	183.4	189.83	6.4339
31	110	Biased-100k	192.63	193.48	0.8482
32	110	Biased-100k	188.63	183.42	-5.2067
34	110	Biased-100k	190.12	190.51	0.3894

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	180.43	182.9	185.98	2.8232	173.76	175.7	179.19	3.0273	-8.1335	-7.197	-6.6689	0.81321
50	184.42	188.38	192.19	2.916	176.35	180.55	185.47	3.3748	-8.2772	-7.8355	-6.7138	0.63436
60	183.51	186.56	190.82	3.098	175.05	178.87	180.56	2.1889	-10.893	-7.687	-3.1365	2.8663
100	182.28	187.11	192.41	4.1765	180.61	185.53	192.07	4.3329	-3.1079	-1.5835	-0.3404	1.103
110	183.4	188.45	192.63	3.4191	183.42	188.43	193.48	4.1612	-5.2067	-0.02164	6.4339	4.3587

vice Test: 74.15 SYNC_SW_DELAY_VIN_7V(EXT_CLOCK|Delay/SYNC_to_SW3/7/7/////1.8///@SYNC_SW_DELAY_VIN_7





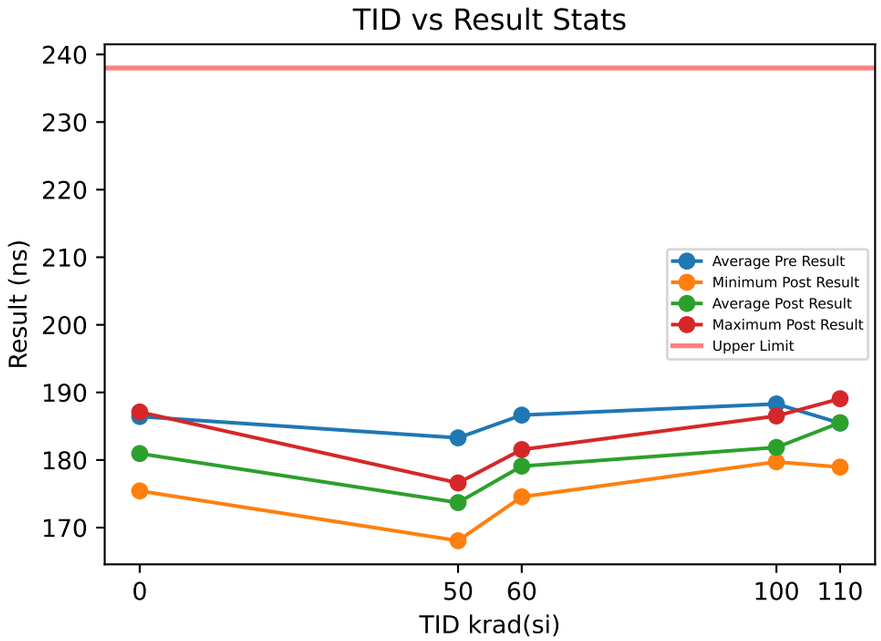
Test Results (Upper Limit = 238.0 (ns))

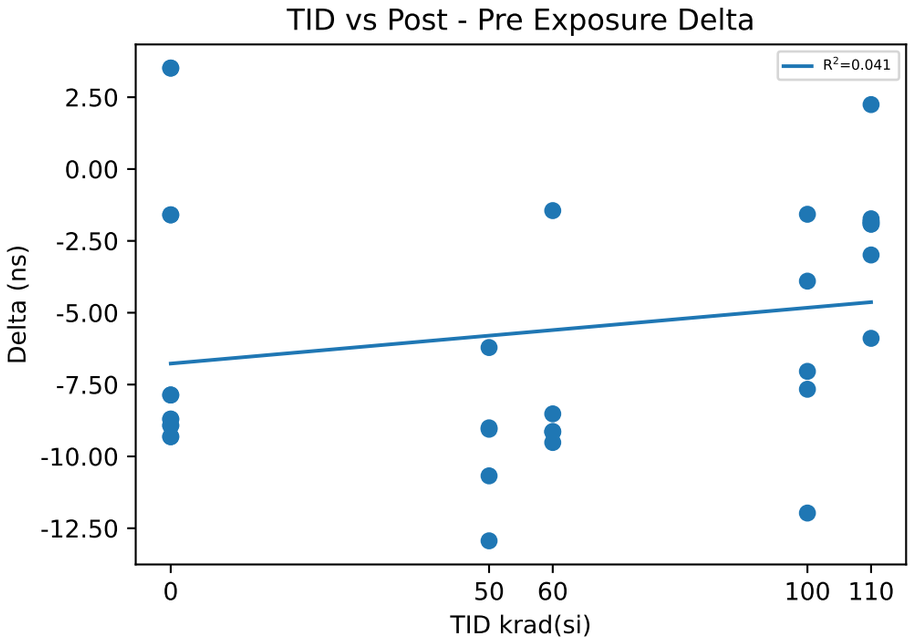
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	181.44	173.32	-8.1134
2	0	CU2	183.91	175.63	-8.2797
3	0	CU3	180.64	171.18	-9.4599
11	50	Unbiased-50k	182.5	172.44	-10.064
12	50	Unbiased-50k	188.6	180.28	-8.3226
13	50	Unbiased-50k	179.06	169.59	-9.4631
14	50	Unbiased-50k	182.51	173.18	-9.3296
16	50	Unbiased-50k	185.31	177.54	-7.7668
17	60	Biased-50k	177.98	171.05	-6.9359
18	60	Biased-50k	190.23	182.15	-8.0827
19	60	Biased-50k	180.41	171.18	-9.2302
20	60	Biased-50k	187.95	178.6	-9.353
21	60	Biased-50k	193.76	184.28	-9.4772
24	100	Unbiased-100k	188.65	174.03	-14.617
25	100	Unbiased-100k	181.83	180.14	-1.6912
26	100	Unbiased-100k	187.96	190.15	2.1905
27	100	Unbiased-100k	192.38	190.79	-1.5882
28	100	Unbiased-100k	188.34	188.22	-0.1209
29	110	Biased-100k	188.29	187.22	-1.0753
30	110	Biased-100k	177.35	182.65	5.3024
31	110	Biased-100k	188.72	188.28	-0.4363
32	110	Biased-100k	185.68	179.79	-5.8901
34	110	Biased-100k	191.53	188.73	-2.7906

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	180.64	182	183.91	1.7051	171.18	173.38	175.63	2.2249	-9.4599	-8.6177	-8.1134	0.73412
50	179.06	183.6	188.6	3.5712	169.59	174.61	180.28	4.2634	-10.064	-8.9893	-7.7668	0.9267
60	177.98	186.07	193.76	6.6581	171.05	177.45	184.28	6.1298	-9.4772	-8.6158	-6.9359	1.0919
100	181.83	187.83	192.38	3.7952	174.03	184.67	190.79	7.3091	-14.617	-3.1653	2.1905	6.5908
110	177.35	186.31	191.53	5.4229	179.79	185.33	188.73	3.9295	-5.8901	-0.97798	5.3024	4.0976

vice Test: 74.16 SYNC_SW_DELAY_VIN_7V(EXT_CLOCK|Delay/SYNC_to_SW4/7/7/////1.8///@SYNC_SW_DELAY_VIN_7





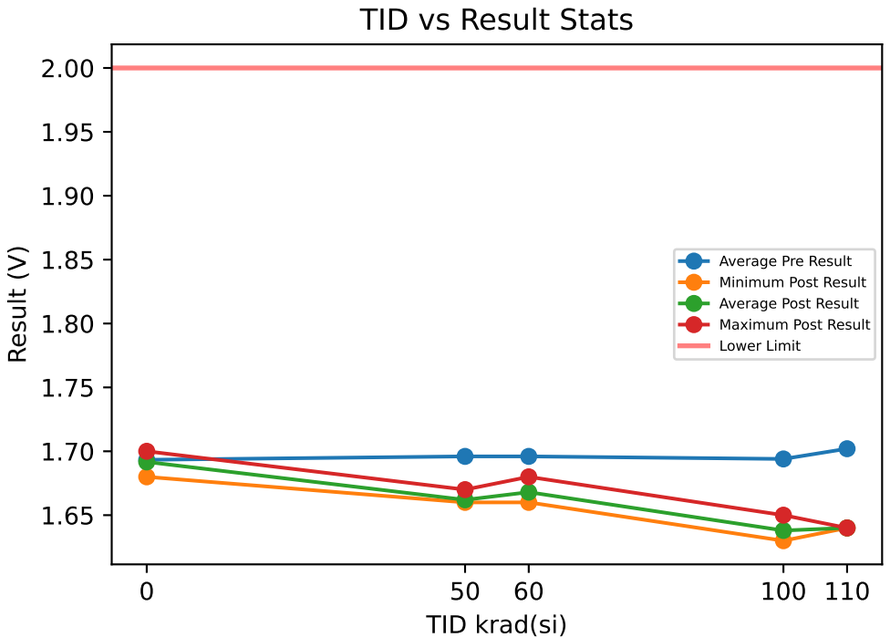
Test Results (Upper Limit = 238.0 (ns))

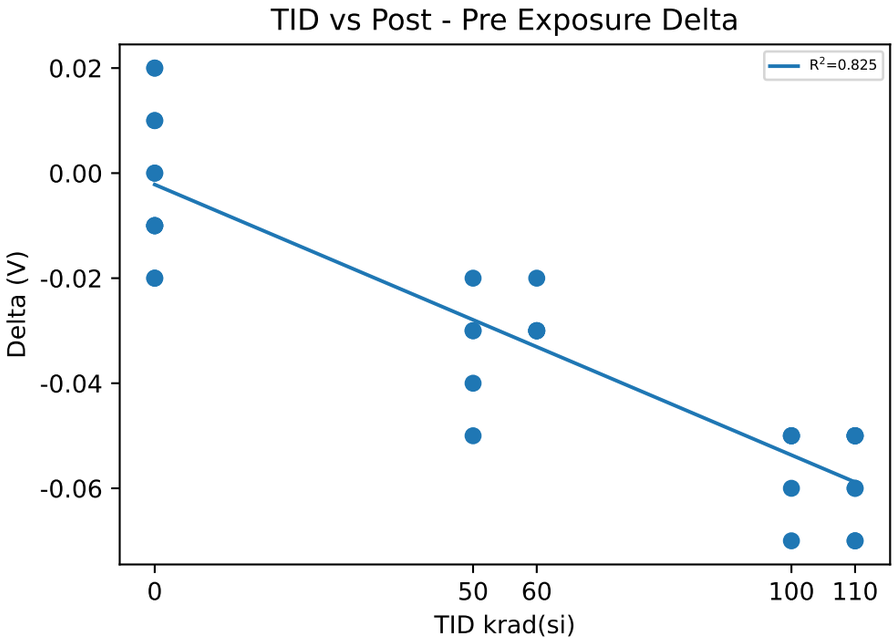
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	183.59	175.73	-7.8631
2	0	CU2	184.13	175.43	-8.7021
3	0	CU3	191.58	182.27	-9.3131
11	50	Unbiased-50k	182.82	176.61	-6.2113
12	50	Unbiased-50k	185.31	176.26	-9.0546
13	50	Unbiased-50k	189.21	176.28	-12.938
14	50	Unbiased-50k	181.98	171.31	-10.677
16	50	Unbiased-50k	177.07	168.06	-9.0062
17	60	Biased-50k	183.7	174.55	-9.1451
18	60	Biased-50k	189.36	180.84	-8.5192
19	60	Biased-50k	179.93	178.48	-1.4468
20	60	Biased-50k	191.06	181.54	-9.5162
21	60	Biased-50k	189.17	180.04	-9.1345
24	100	Unbiased-100k	187.39	179.73	-7.6634
25	100	Unbiased-100k	188.09	186.52	-1.5742
26	100	Unbiased-100k	184.22	180.31	-3.9006
27	100	Unbiased-100k	192.05	180.08	-11.971
28	100	Unbiased-100k	189.73	182.69	-7.0408
29	110	Biased-100k	183.93	180.94	-2.9902
30	110	Biased-100k	180.68	178.95	-1.7306
31	110	Biased-100k	187.08	181.19	-5.8914
32	110	Biased-100k	184.72	186.97	2.2431
34	110	Biased-100k	190.9	189.07	-1.831

Test Statistics (ns)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	183.59	186.43	191.58	4.4657	175.43	177.81	182.27	3.8655	-9.3131	-8.6261	-7.8631	0.72798
50	177.07	183.28	189.21	4.4673	168.06	173.7	176.61	3.8451	-12.938	-9.5773	-6.2113	2.4713
60	179.93	186.64	191.06	4.6639	174.55	179.09	181.54	2.781	-9.5162	-7.5524	-1.4468	3.4318
100	184.22	188.3	192.05	2.8993	179.73	181.87	186.52	2.8492	-11.971	-6.43	-1.5742	3.9551
110	180.68	185.46	190.9	3.8051	178.95	183.42	189.07	4.3464	-5.8914	-2.04	2.2431	2.9249

Device Test: 74.17 SYNC_SW_VIH_VIN_7V(EXT_CLOCK|VIH/SYNC/7/7/////1.8///@SYNC_SW_VIH_VIN_7V)





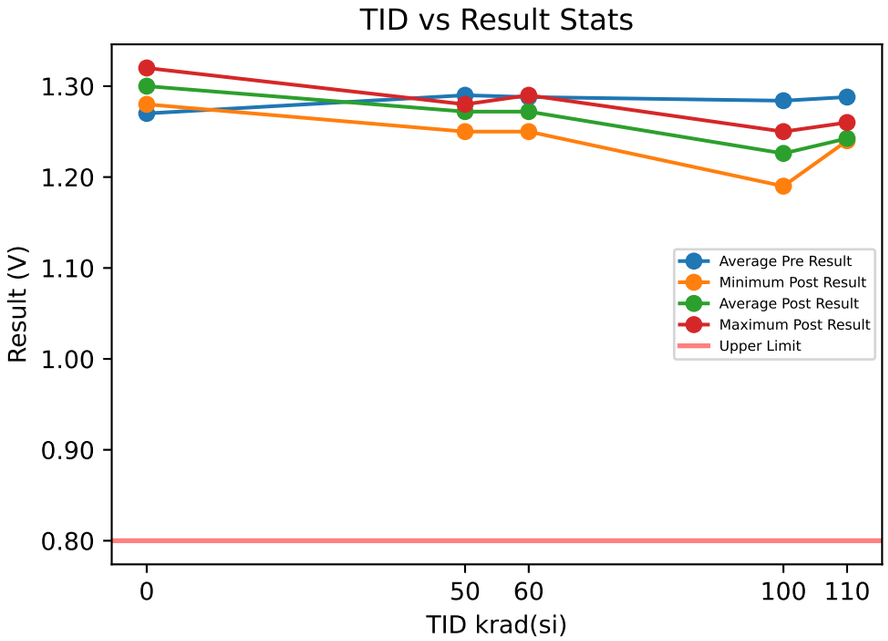
Test Results (Lower Limit = 2.0 (V))

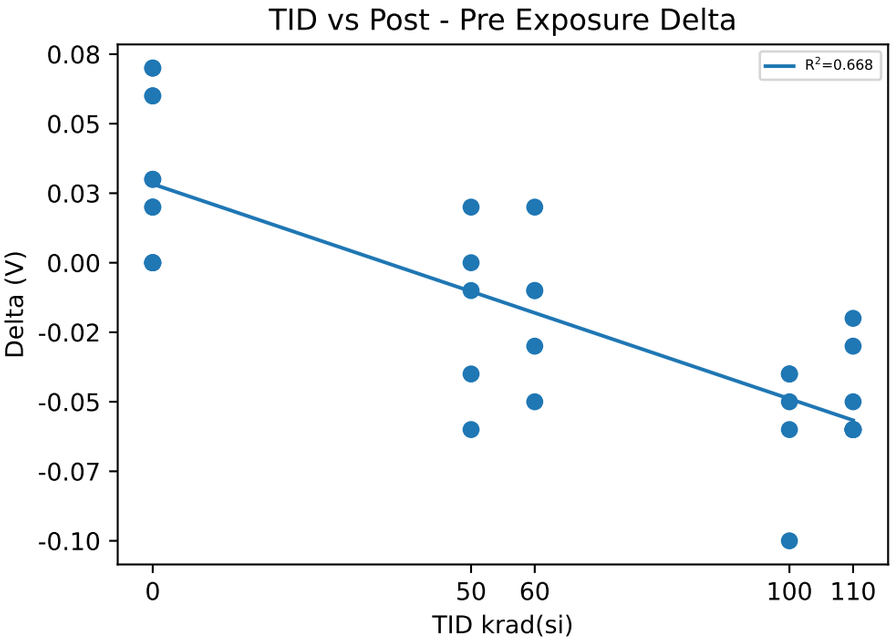
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.7	1.69	-0.01
2	0	CU2	1.7	1.7	0
3	0	CU3	1.68	1.69	0.01
11	50	Unbiased-50k	1.69	1.66	-0.03
12	50	Unbiased-50k	1.7	1.66	-0.04
13	50	Unbiased-50k	1.69	1.67	-0.02
14	50	Unbiased-50k	1.71	1.66	-0.05
16	50	Unbiased-50k	1.69	1.66	-0.03
17	60	Biased-50k	1.69	1.66	-0.03
18	60	Biased-50k	1.7	1.68	-0.02
19	60	Biased-50k	1.7	1.67	-0.03
20	60	Biased-50k	1.7	1.67	-0.03
21	60	Biased-50k	1.69	1.66	-0.03
24	100	Unbiased-100k	1.69	1.63	-0.06
25	100	Unbiased-100k	1.7	1.65	-0.05
26	100	Unbiased-100k	1.69	1.64	-0.05
27	100	Unbiased-100k	1.71	1.64	-0.07
28	100	Unbiased-100k	1.68	1.63	-0.05
29	110	Biased-100k	1.71	1.64	-0.07
30	110	Biased-100k	1.7	1.64	-0.06
31	110	Biased-100k	1.71	1.64	-0.07
32	110	Biased-100k	1.7	1.64	-0.06
34	110	Biased-100k	1.69	1.64	-0.05

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.68	1.6933	1.7	0.011547	1.69	1.6933	1.7	0.0057735	-0.01	0	0.01	0.01
50	1.69	1.696	1.71	0.0089443	1.66	1.662	1.67	0.0044721	-0.05	-0.034	-0.02	0.011402
60	1.69	1.696	1.7	0.0054772	1.66	1.668	1.68	0.0083666	-0.03	-0.028	-0.02	0.0044721
100	1.68	1.694	1.71	0.011402	1.63	1.638	1.65	0.0083666	-0.07	-0.056	-0.05	0.0089443
110	1.69	1.702	1.71	0.0083666	1.64	1.64	1.64	0	-0.07	-0.062	-0.05	0.0083666

Device Test: 74.18 SYNC_VIL(EXT_CLOCK|VIL/SYNC/7/7/////1.8///@SYNC_VIL)





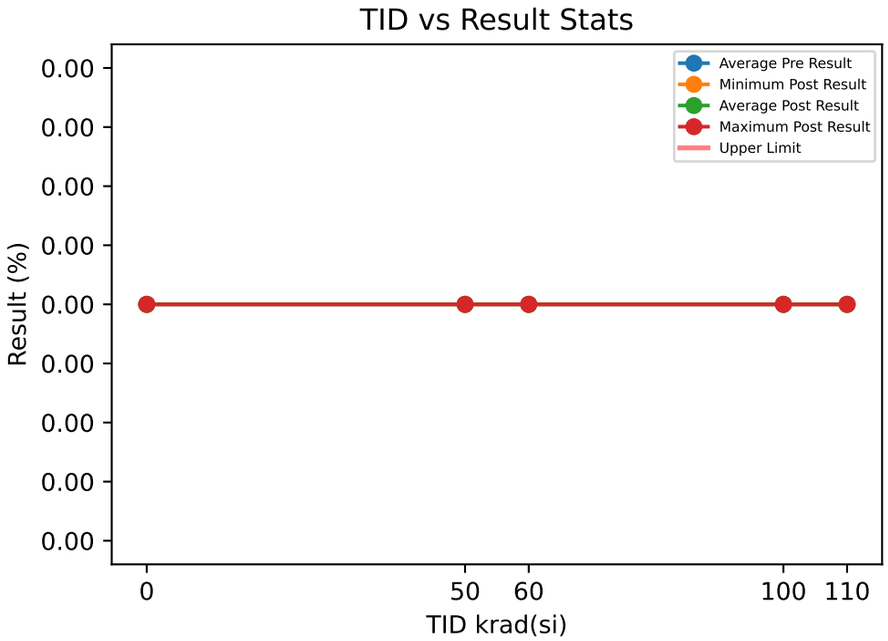
Test Results (Upper Limit = 0.8 (V))

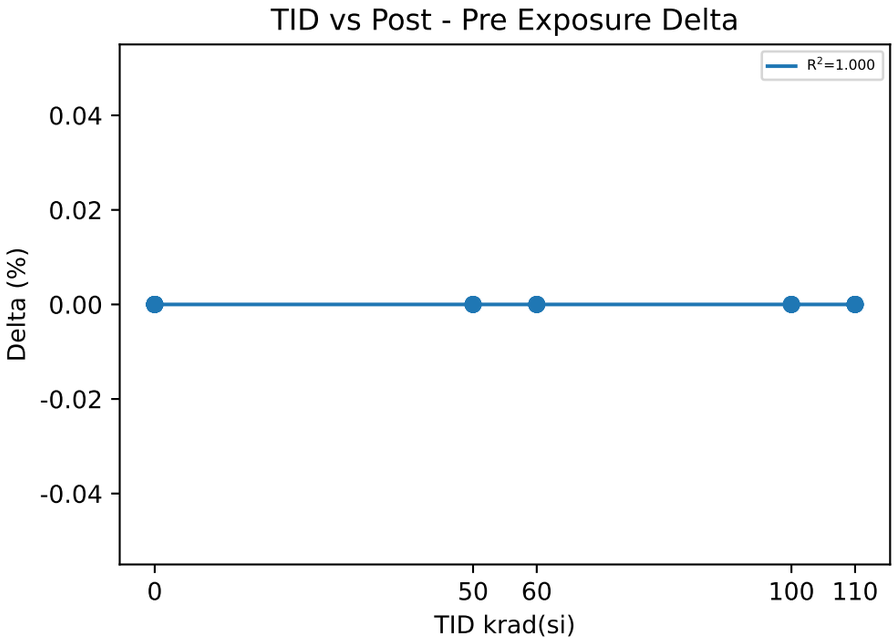
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1.28	1.28	0
2	0	CU2	1.24	1.3	0.06
3	0	CU3	1.29	1.29	0
11	50	Unbiased-50k	1.29	1.28	-0.01
12	50	Unbiased-50k	1.31	1.25	-0.06
13	50	Unbiased-50k	1.31	1.27	-0.04
14	50	Unbiased-50k	1.28	1.28	0
16	50	Unbiased-50k	1.26	1.28	0.02
17	60	Biased-50k	1.29	1.28	-0.01
18	60	Biased-50k	1.3	1.29	-0.01
19	60	Biased-50k	1.26	1.28	0.02
20	60	Biased-50k	1.3	1.25	-0.05
21	60	Biased-50k	1.29	1.26	-0.03
24	100	Unbiased-100k	1.3	1.25	-0.05
25	100	Unbiased-100k	1.25	1.21	-0.04
26	100	Unbiased-100k	1.29	1.19	-0.1
27	100	Unbiased-100k	1.3	1.24	-0.06
28	100	Unbiased-100k	1.28	1.24	-0.04
29	110	Biased-100k	1.28	1.26	-0.02
30	110	Biased-100k	1.27	1.24	-0.03
31	110	Biased-100k	1.29	1.24	-0.05
32	110	Biased-100k	1.3	1.24	-0.06
34	110	Biased-100k	1.3	1.24	-0.06

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.24	1.27	1.29	0.026458	1.28	1.29	1.3	0.01	0	0.02	0.06	0.034641
50	1.26	1.29	1.31	0.021213	1.25	1.272	1.28	0.013038	-0.06	-0.018	0.02	0.031937
60	1.26	1.288	1.3	0.016432	1.25	1.272	1.29	0.016432	-0.05	-0.016	0.02	0.026077
100	1.25	1.284	1.3	0.020736	1.19	1.226	1.25	0.0251	-0.1	-0.058	-0.04	0.0249
110	1.27	1.288	1.3	0.013038	1.24	1.244	1.26	0.0089443	-0.06	-0.044	-0.02	0.018166

Test: 74.19 SYNC_IN_DUTY_CYCLE_LOW(EXT_CLOCK|GNG_DutyCyc40Pct/SYNC/7/7/////1.8///@SYNC_IN_DUTY_CYCL





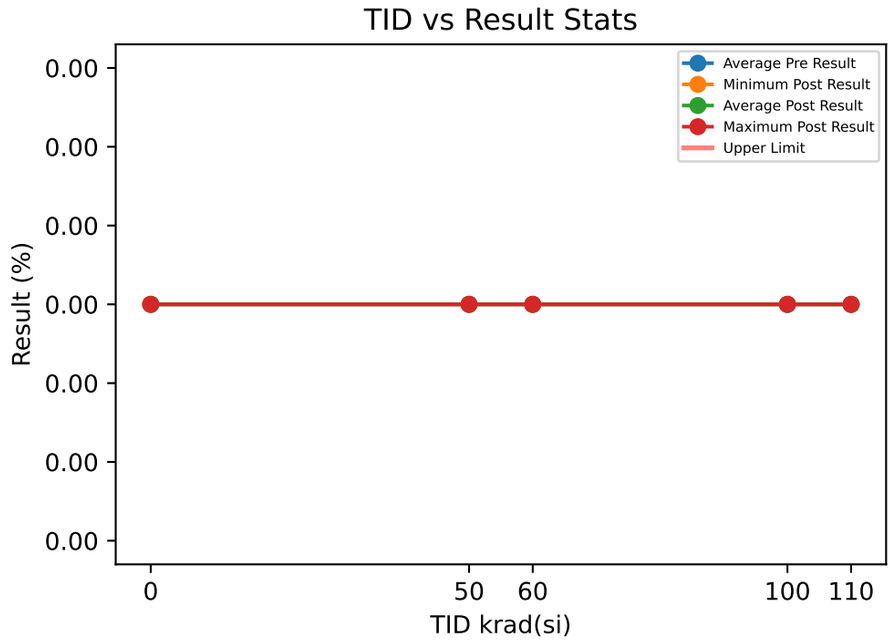
Test Results (No Limits Specified (%))

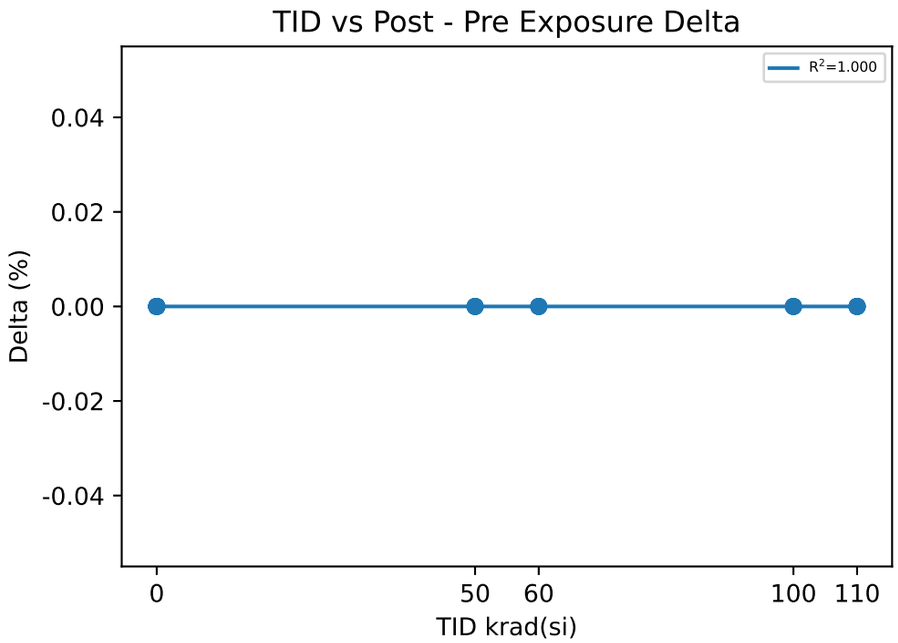
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	4e-13	4e-13	0
2	0	CU2	4e-13	4e-13	0
3	0	CU3	4e-13	4e-13	0
11	50	Unbiased-50k	4e-13	4e-13	0
12	50	Unbiased-50k	4e-13	4e-13	0
13	50	Unbiased-50k	4e-13	4e-13	0
14	50	Unbiased-50k	4e-13	4e-13	0
16	50	Unbiased-50k	4e-13	4e-13	0
17	60	Biased-50k	4e-13	4e-13	0
18	60	Biased-50k	4e-13	4e-13	0
19	60	Biased-50k	4e-13	4e-13	0
20	60	Biased-50k	4e-13	4e-13	0
21	60	Biased-50k	4e-13	4e-13	0
24	100	Unbiased-100k	4e-13	4e-13	0
25	100	Unbiased-100k	4e-13	4e-13	0
26	100	Unbiased-100k	4e-13	4e-13	0
27	100	Unbiased-100k	4e-13	4e-13	0
28	100	Unbiased-100k	4e-13	4e-13	0
29	110	Biased-100k	4e-13	4e-13	0
30	110	Biased-100k	4e-13	4e-13	0
31	110	Biased-100k	4e-13	4e-13	0
32	110	Biased-100k	4e-13	4e-13	0
34	110	Biased-100k	4e-13	4e-13	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
50	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
60	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
100	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0
110	4e-13	4e-13	4e-13	0	4e-13	4e-13	4e-13	0	0	0	0	0

Test: 74.20 SYNC_IN_DUTY_CYCLE_HIGH(EXT_CLOCK|GNG_DutyCyc60Pct/SYNC/7/7/////1.8///@SYNC_IN_DUTY_CYCL





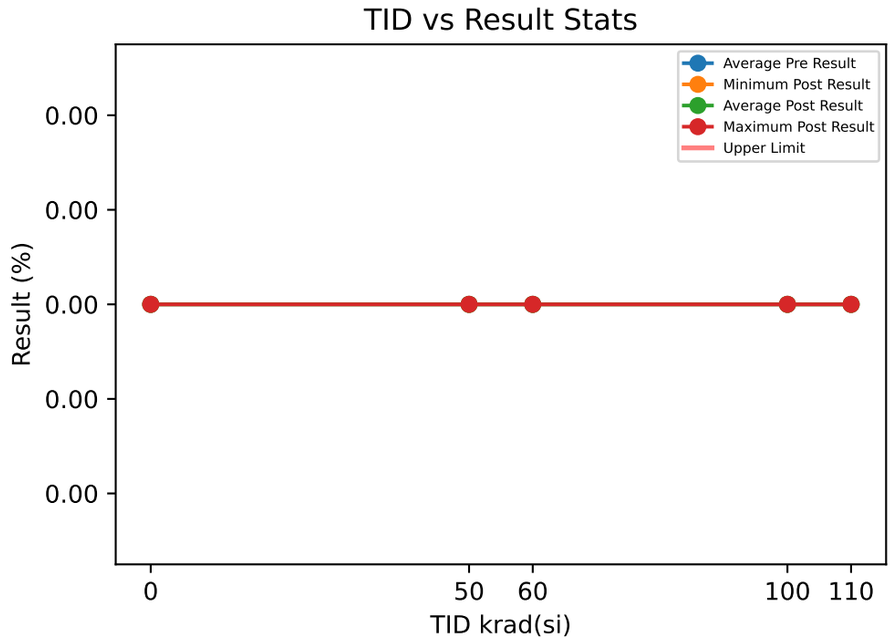
Test Results (No Limits Specified (%))

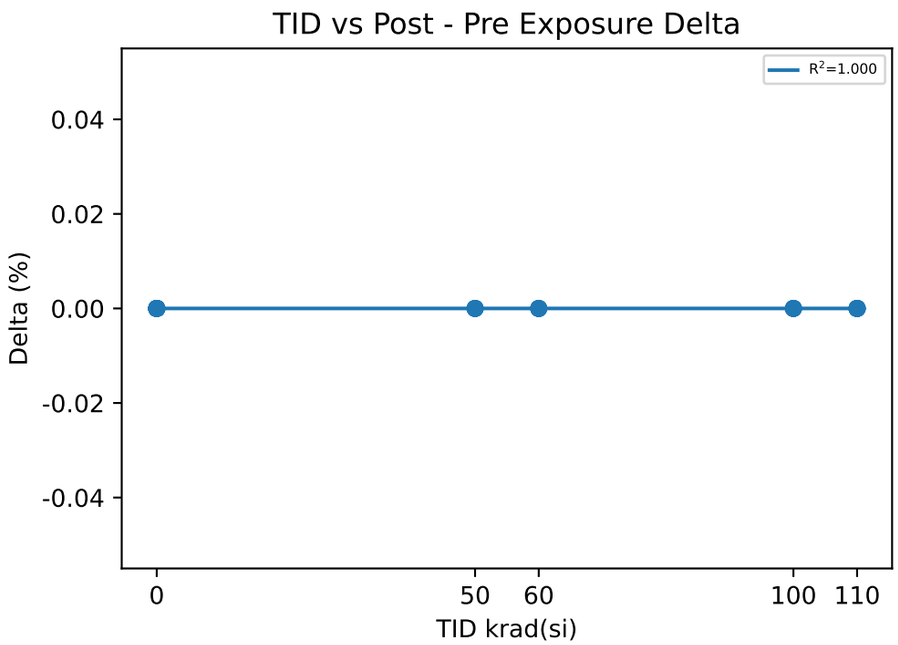
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6e-13	6e-13	0
2	0	CU2	6e-13	6e-13	0
3	0	CU3	6e-13	6e-13	0
11	50	Unbiased-50k	6e-13	6e-13	0
12	50	Unbiased-50k	6e-13	6e-13	0
13	50	Unbiased-50k	6e-13	6e-13	0
14	50	Unbiased-50k	6e-13	6e-13	0
16	50	Unbiased-50k	6e-13	6e-13	0
17	60	Biased-50k	6e-13	6e-13	0
18	60	Biased-50k	6e-13	6e-13	0
19	60	Biased-50k	6e-13	6e-13	0
20	60	Biased-50k	6e-13	6e-13	0
21	60	Biased-50k	6e-13	6e-13	0
24	100	Unbiased-100k	6e-13	6e-13	0
25	100	Unbiased-100k	6e-13	6e-13	0
26	100	Unbiased-100k	6e-13	6e-13	0
27	100	Unbiased-100k	6e-13	6e-13	0
28	100	Unbiased-100k	6e-13	6e-13	0
29	110	Biased-100k	6e-13	6e-13	0
30	110	Biased-100k	6e-13	6e-13	0
31	110	Biased-100k	6e-13	6e-13	0
32	110	Biased-100k	6e-13	6e-13	0
34	110	Biased-100k	6e-13	6e-13	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
50	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
60	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
100	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0
110	6e-13	6e-13	6e-13	0	6e-13	6e-13	6e-13	0	0	0	0	0

t: 74.21 SYNC_IN_DUTY_CYCLE_RANGE(EXT_CLOCK|GNG_DutyCycRange/SYNC/7/7//////1.8///@SYNC_IN_DUTY_CYCL





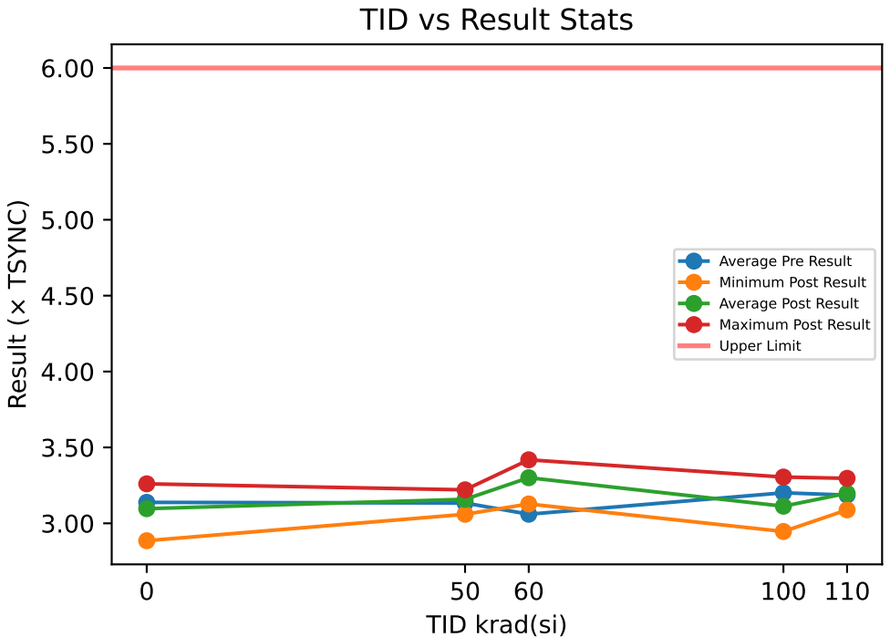
Test Results (No Limits Specified (%))

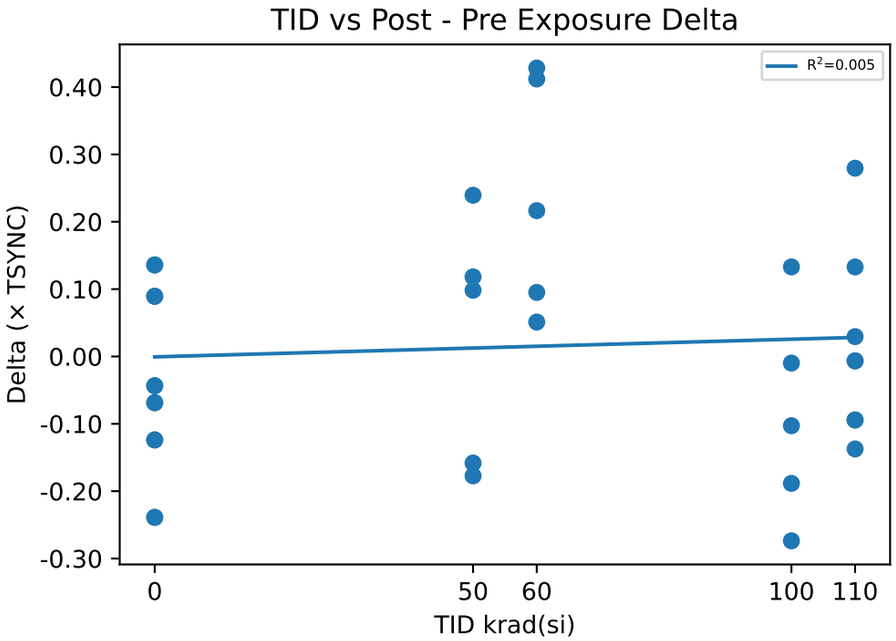
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5e-13	5e-13	0
2	0	CU2	5e-13	5e-13	0
3	0	CU3	5e-13	5e-13	0
11	50	Unbiased-50k	5e-13	5e-13	0
12	50	Unbiased-50k	5e-13	5e-13	0
13	50	Unbiased-50k	5e-13	5e-13	0
14	50	Unbiased-50k	5e-13	5e-13	0
16	50	Unbiased-50k	5e-13	5e-13	0
17	60	Biased-50k	5e-13	5e-13	0
18	60	Biased-50k	5e-13	5e-13	0
19	60	Biased-50k	5e-13	5e-13	0
20	60	Biased-50k	5e-13	5e-13	0
21	60	Biased-50k	5e-13	5e-13	0
24	100	Unbiased-100k	5e-13	5e-13	0
25	100	Unbiased-100k	5e-13	5e-13	0
26	100	Unbiased-100k	5e-13	5e-13	0
27	100	Unbiased-100k	5e-13	5e-13	0
28	100	Unbiased-100k	5e-13	5e-13	0
29	110	Biased-100k	5e-13	5e-13	0
30	110	Biased-100k	5e-13	5e-13	0
31	110	Biased-100k	5e-13	5e-13	0
32	110	Biased-100k	5e-13	5e-13	0
34	110	Biased-100k	5e-13	5e-13	0

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
50	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
60	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
100	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0
110	5e-13	5e-13	5e-13	0	5e-13	5e-13	5e-13	0	0	0	0	0

Device Test: 74.22 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW1/7/7//////1.8///@T_CLOCK_DET)





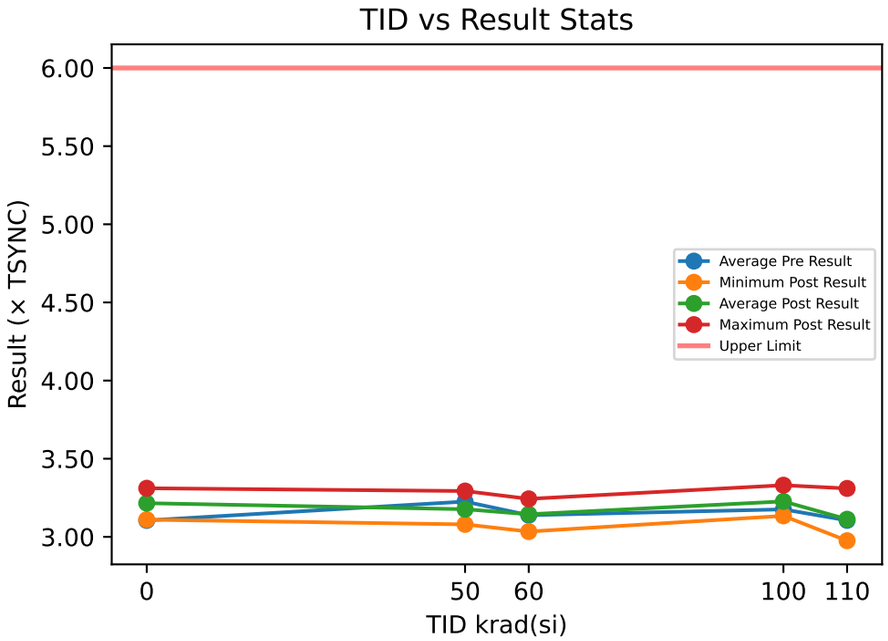
Test Results (Upper Limit = 6.0 (× TSYNC))

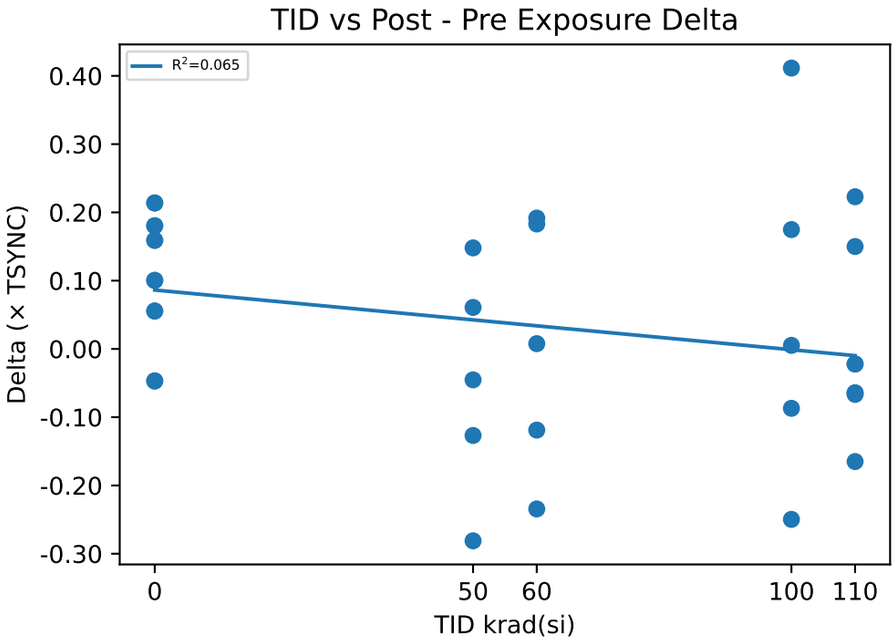
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.2027	3.1592	-0.0435
2	0	CU2	3.1243	3.2602	0.1359
3	0	CU3	3.0873	2.9634	-0.1239
11	50	Unbiased-50k	3.2805	3.1223	-0.1582
12	50	Unbiased-50k	2.9813	3.2207	0.2394
13	50	Unbiased-50k	3.2368	3.0596	-0.1772
14	50	Unbiased-50k	3.0548	3.173	0.1182
16	50	Unbiased-50k	3.1164	3.2147	0.0983
17	60	Biased-50k	3.202	3.4185	0.2165
18	60	Biased-50k	2.9073	3.3355	0.4282
19	60	Biased-50k	2.9498	3.3618	0.412
20	60	Biased-50k	3.1642	3.2593	0.0951
21	60	Biased-50k	3.0764	3.1275	0.0511
24	100	Unbiased-100k	3.0483	3.1813	0.133
25	100	Unbiased-100k	3.2199	2.9462	-0.2737
26	100	Unbiased-100k	3.2524	3.1496	-0.1028
27	100	Unbiased-100k	3.3146	3.3048	-0.0098
28	100	Unbiased-100k	3.1705	2.9821	-0.1884
29	110	Biased-100k	3.4247	3.2874	-0.1373
30	110	Biased-100k	2.9968	3.2763	0.2795
31	110	Biased-100k	3.163	3.1925	0.0295
32	110	Biased-100k	3.1635	3.2964	0.1329
34	110	Biased-100k	3.1829	3.0886	-0.0943

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.0873	3.1381	3.2027	0.058925	2.9634	3.1276	3.2602	0.1509	-0.1239	-0.0105	0.1359	0.13301
50	2.9813	3.134	3.2805	0.12443	3.0596	3.1581	3.2207	0.067691	-0.1772	0.0241	0.2394	0.18335
60	2.9073	3.0599	3.202	0.12918	3.1275	3.3005	3.4185	0.1124	0.0511	0.24058	0.4282	0.17481
100	3.0483	3.2011	3.3146	0.10019	2.9462	3.1128	3.3048	0.14811	-0.2737	-0.08834	0.133	0.15791
110	2.9968	3.1862	3.4247	0.15315	3.0886	3.2282	3.2964	0.088363	-0.1373	0.04206	0.2795	0.16996

Device Test: 74.23 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW2/7/7/////1.8///@T_CLOCK_DET)





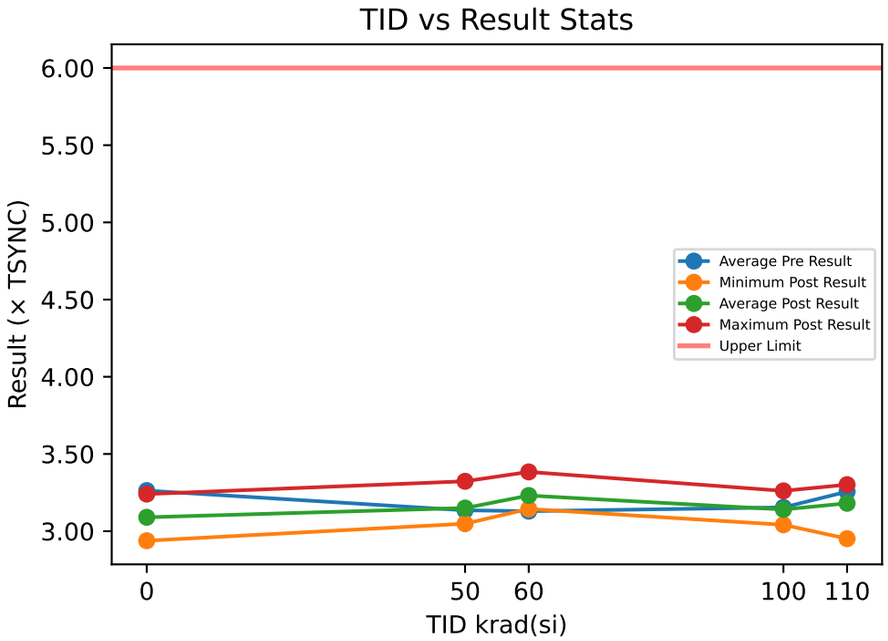
Test Results (Upper Limit = 6.0 (× TSYNC))

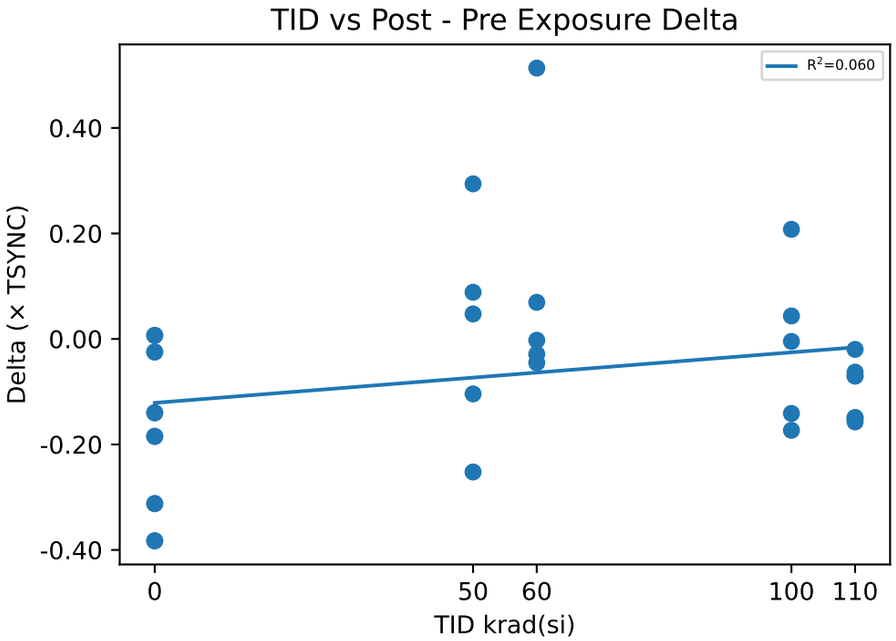
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.0066	3.187	0.1804
2	0	CU2	3.157	3.1101	-0.0469
3	0	CU3	3.1519	3.311	0.1591
11	50	Unbiased-50k	3.1453	3.2933	0.148
12	50	Unbiased-50k	3.3424	3.2156	-0.1268
13	50	Unbiased-50k	3.0707	3.1315	0.0608
14	50	Unbiased-50k	3.4457	3.1646	-0.2811
16	50	Unbiased-50k	3.1252	3.0799	-0.0453
17	60	Biased-50k	3.0602	3.2432	0.183
18	60	Biased-50k	3.1529	3.034	-0.1189
19	60	Biased-50k	3.3845	3.1501	-0.2344
20	60	Biased-50k	3.0538	3.0615	0.0077
21	60	Biased-50k	3.0426	3.2343	0.1917
24	100	Unbiased-100k	3.4354	3.1857	-0.2497
25	100	Unbiased-100k	3.2214	3.1344	-0.087
26	100	Unbiased-100k	2.8831	3.2945	0.4114
27	100	Unbiased-100k	3.3253	3.3305	0.0052
28	100	Unbiased-100k	3.0148	3.1896	0.1748
29	110	Biased-100k	3.047	3.197	0.15
30	110	Biased-100k	3.087	3.3099	0.2229
31	110	Biased-100k	3.042	2.9754	-0.0666
32	110	Biased-100k	3.2172	3.0522	-0.165
34	110	Biased-100k	3.1352	3.1131	-0.0221

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.0066	3.1052	3.157	0.085399	3.1101	3.2027	3.311	0.10137	-0.0469	0.097533	0.1804	0.12554
50	3.0707	3.2259	3.4457	0.16016	3.0799	3.177	3.2933	0.081652	-0.2811	-0.04888	0.148	0.16643
60	3.0426	3.1388	3.3845	0.14424	3.034	3.1446	3.2432	0.096094	-0.2344	0.00582	0.1917	0.18655
100	2.8831	3.176	3.4354	0.22551	3.1344	3.2269	3.3305	0.082079	-0.2497	0.05094	0.4114	0.25337
110	3.042	3.1057	3.2172	0.072725	2.9754	3.1295	3.3099	0.12951	-0.165	0.02384	0.2229	0.15929

Device Test: 74.24 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW3/7/7//////1.8///@T_CLOCK_DET)





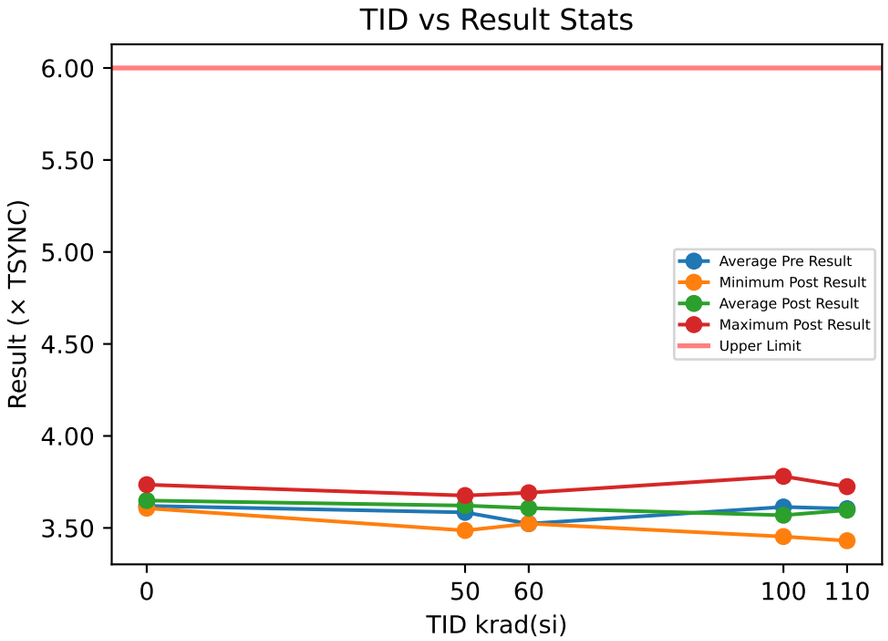
Test Results (Upper Limit = 6.0 (× TSYNC))

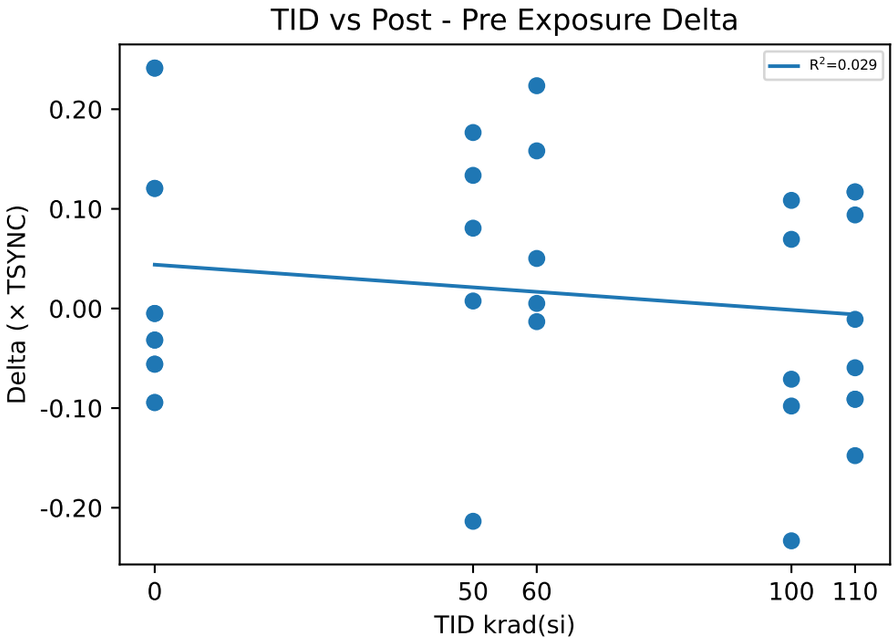
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.2341	3.0942	-0.1399
2	0	CU2	3.3209	3.0087	-0.3122
3	0	CU3	3.2335	3.0488	-0.1847
11	50	Unbiased-50k	3.3017	3.0495	-0.2522
12	50	Unbiased-50k	3.1526	3.0484	-0.1042
13	50	Unbiased-50k	3.0291	3.3231	0.294
14	50	Unbiased-50k	3.0195	3.0669	0.0474
16	50	Unbiased-50k	3.1732	3.2617	0.0885
17	60	Biased-50k	3.3567	3.3115	-0.0452
18	60	Biased-50k	3.1499	3.1474	-0.0025
19	60	Biased-50k	3.1962	3.1674	-0.0288
20	60	Biased-50k	2.8704	3.3839	0.5135
21	60	Biased-50k	3.0746	3.144	0.0694
24	100	Unbiased-100k	3.0532	3.261	0.2078
25	100	Unbiased-100k	3.3252	3.184	-0.1412
26	100	Unbiased-100k	3.1075	3.1511	0.0436
27	100	Unbiased-100k	3.2146	3.0414	-0.1732
28	100	Unbiased-100k	3.069	3.0644	-0.0046
29	110	Biased-100k	3.3037	3.1512	-0.1525
30	110	Biased-100k	3.1088	2.9515	-0.1573
31	110	Biased-100k	3.1716	3.1518	-0.0198
32	110	Biased-100k	3.3642	3.3013	-0.0629
34	110	Biased-100k	3.332	3.2617	-0.0703

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.2335	3.2628	3.3209	0.050288	3.0087	3.0506	3.0942	0.042777	-0.3122	-0.21227	-0.1399	0.089397
50	3.0195	3.1352	3.3017	0.11631	3.0484	3.1499	3.3231	0.13207	-0.2522	0.0147	0.294	0.20609
60	2.8704	3.1296	3.3567	0.17793	3.144	3.2308	3.3839	0.11007	-0.0452	0.10128	0.5135	0.23457
100	3.0532	3.1539	3.3252	0.1146	3.0414	3.1404	3.261	0.089634	-0.1732	-0.01352	0.2078	0.1534
110	3.1088	3.2561	3.3642	0.11017	2.9515	3.1635	3.3013	0.13589	-0.1573	-0.09256	-0.0198	0.060111

Device Test: 74.25 T_CLOCK_DET(EXT_CLOCK|ExtToIntClkDetect/SW4/7/7/////1.8///@T_CLOCK_DET)





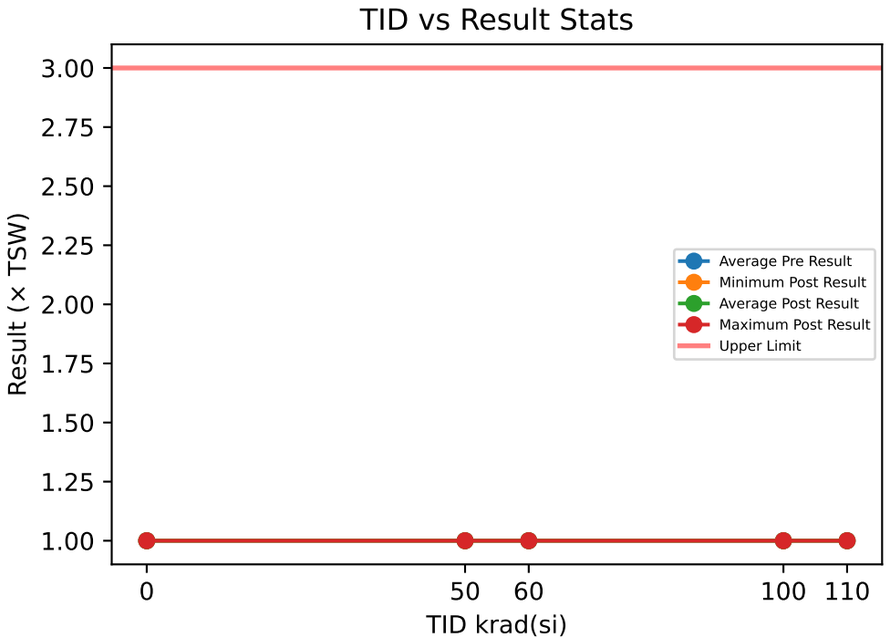
Test Results (Upper Limit = 6.0 (× TSYNC))

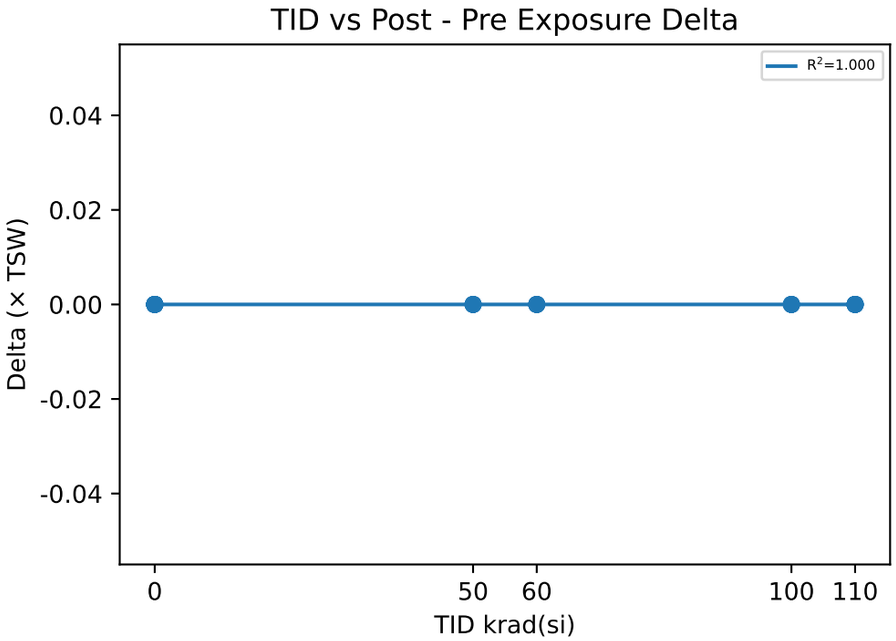
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	3.7025	3.6081	-0.0944
2	0	CU2	3.4938	3.7351	0.2413
3	0	CU3	3.663	3.6071	-0.0559
11	50	Unbiased-50k	3.4897	3.6663	0.1766
12	50	Unbiased-50k	3.5955	3.6761	0.0806
13	50	Unbiased-50k	3.4942	3.6278	0.1336
14	50	Unbiased-50k	3.6435	3.651	0.0075
16	50	Unbiased-50k	3.6997	3.4861	-0.2136
17	60	Biased-50k	3.5482	3.5533	0.0051
18	60	Biased-50k	3.4983	3.6565	0.1582
19	60	Biased-50k	3.5649	3.6151	0.0502
20	60	Biased-50k	3.4676	3.6912	0.2236
21	60	Biased-50k	3.5367	3.5235	-0.0132
24	100	Unbiased-100k	3.7052	3.6073	-0.0979
25	100	Unbiased-100k	3.524	3.453	-0.071
26	100	Unbiased-100k	3.4517	3.5211	0.0694
27	100	Unbiased-100k	3.7167	3.4835	-0.2332
28	100	Unbiased-100k	3.6719	3.7804	0.1085
29	110	Biased-100k	3.5782	3.4305	-0.1477
30	110	Biased-100k	3.587	3.5761	-0.0109
31	110	Biased-100k	3.6267	3.5672	-0.0595
32	110	Biased-100k	3.6239	3.7178	0.0939
34	110	Biased-100k	3.6073	3.7243	0.117

Test Statistics (× TSYNC)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.4938	3.6198	3.7025	0.11086	3.6071	3.6501	3.7351	0.073614	-0.0944	0.030333	0.2413	0.18371
50	3.4897	3.5845	3.6997	0.092215	3.4861	3.6215	3.6761	0.077832	-0.2136	0.03694	0.1766	0.15362
60	3.4676	3.5231	3.5649	0.039552	3.5235	3.6079	3.6912	0.069745	-0.0132	0.08478	0.2236	0.10223
100	3.4517	3.6139	3.7167	0.11902	3.453	3.5691	3.7804	0.13155	-0.2332	-0.04484	0.1085	0.13743
110	3.5782	3.6046	3.6267	0.02165	3.4305	3.6032	3.7243	0.12212	-0.1477	-0.00144	0.117	0.10951

Device Test: 74.28 T_CLOCK_DET_EXT(EXT_CLOCK|IntToExtClkDetect/GNG_SW1/7/7/////1.8///@T_CLOCK_DET_EXT)





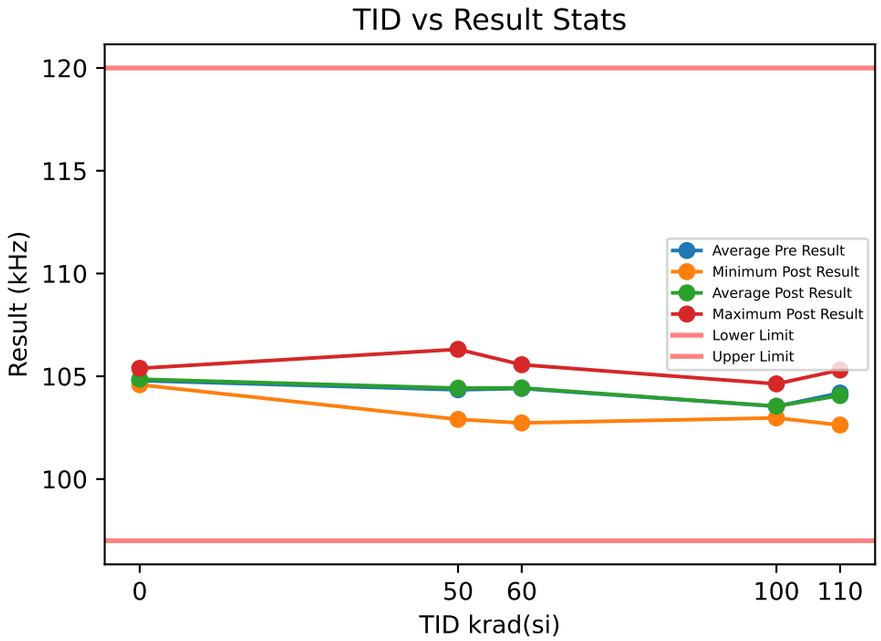
Test Results (Upper Limit = 3.0 (× TSW))

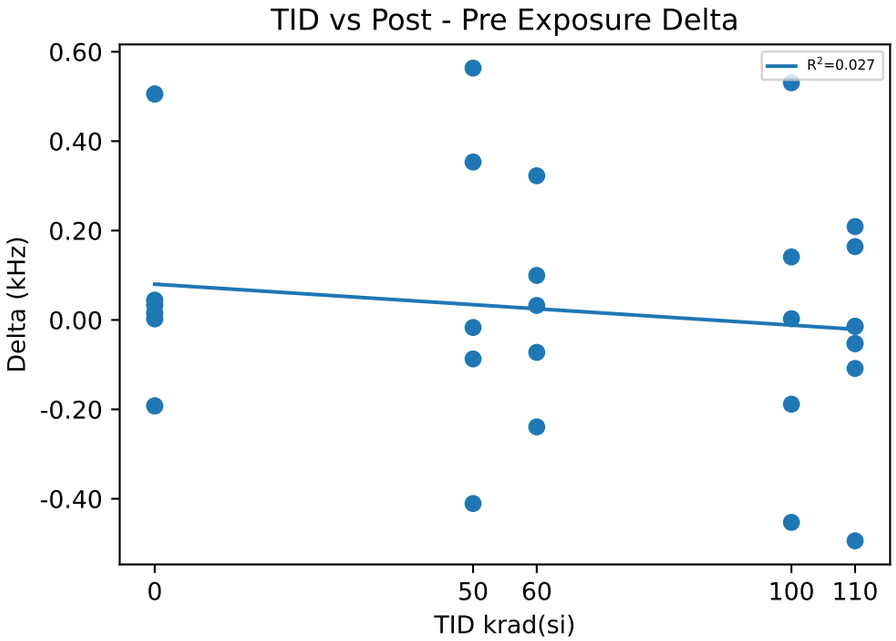
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1	1	0
2	0	CU2	1	1	0
3	0	CU3	1	1	0
11	50	Unbiased-50k	1	1	0
12	50	Unbiased-50k	1	1	0
13	50	Unbiased-50k	1	1	0
14	50	Unbiased-50k	1	1	0
16	50	Unbiased-50k	1	1	0
17	60	Biased-50k	1	1	0
18	60	Biased-50k	1	1	0
19	60	Biased-50k	1	1	0
20	60	Biased-50k	1	1	0
21	60	Biased-50k	1	1	0
24	100	Unbiased-100k	1	1	0
25	100	Unbiased-100k	1	1	0
26	100	Unbiased-100k	1	1	0
27	100	Unbiased-100k	1	1	0
28	100	Unbiased-100k	1	1	0
29	110	Biased-100k	1	1	0
30	110	Biased-100k	1	1	0
31	110	Biased-100k	1	1	0
32	110	Biased-100k	1	1	0
34	110	Biased-100k	1	1	0

Test Statistics (× TSW)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1	1	1	0	1	1	1	0	0	0	0	0
50	1	1	1	0	1	1	1	0	0	0	0	0
60	1	1	1	0	1	1	1	0	0	0	0	0
100	1	1	1	0	1	1	1	0	0	0	0	0
110	1	1	1	0	1	1	1	0	0	0	0	0

Device Test: 75.2 EXT_SET_FREQ_100KHZ(IntFreq|Freq/RT_511/7/7///90.9/634//1.8///@EXT_SET_FREQ_100KHZ)





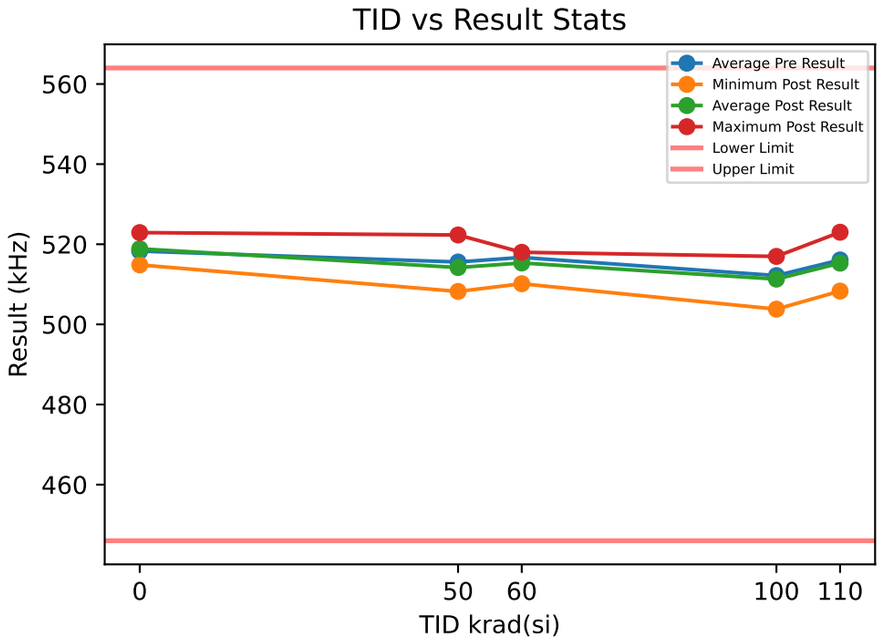
Test Results (Lower Limit = 97.0, Upper Limit = 120.0 (kHz))

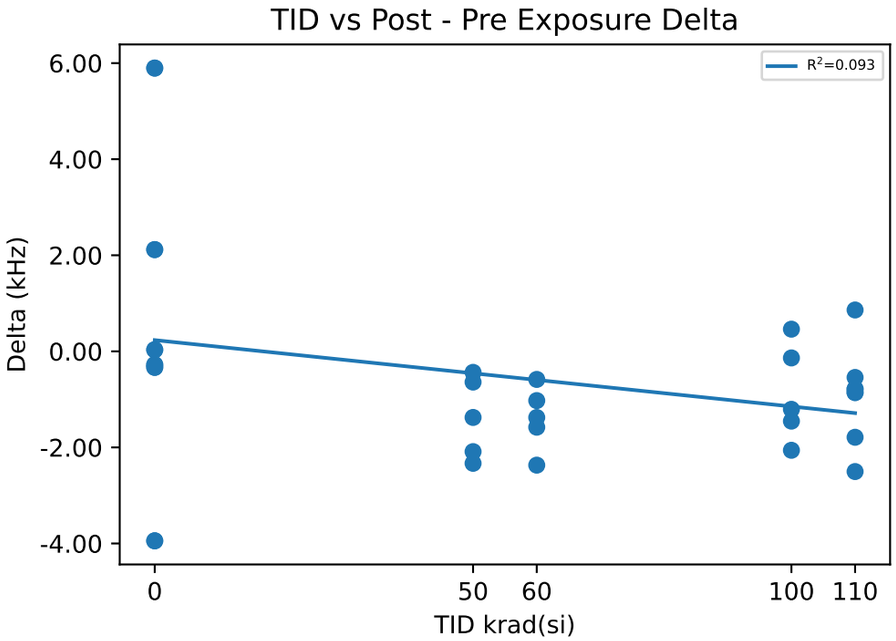
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	104.88	104.89	0.0027
2	0	CU2	104.71	104.72	0.016
3	0	CU3	104.78	104.82	0.044
11	50	Unbiased-50k	103.31	102.9	-0.4107
12	50	Unbiased-50k	104.11	104.1	-0.0169
13	50	Unbiased-50k	104.18	104.54	0.3533
14	50	Unbiased-50k	103.71	104.27	0.5635
16	50	Unbiased-50k	106.4	106.31	-0.0872
17	60	Biased-50k	102.74	102.84	0.0996
18	60	Biased-50k	105.24	105.56	0.3226
19	60	Biased-50k	102.97	102.73	-0.2392
20	60	Biased-50k	105.46	105.49	0.0324
21	60	Biased-50k	105.63	105.55	-0.0725
24	100	Unbiased-100k	103.01	103.01	0.0028
25	100	Unbiased-100k	103.16	102.97	-0.1884
26	100	Unbiased-100k	103.67	103.81	0.141
27	100	Unbiased-100k	102.77	103.3	0.5306
28	100	Unbiased-100k	105.08	104.63	-0.4528
29	110	Biased-100k	102.46	102.63	0.1641
30	110	Biased-100k	105.8	105.3	-0.4941
31	110	Biased-100k	104.92	105.12	0.2089
32	110	Biased-100k	103.78	103.67	-0.1085
34	110	Biased-100k	103.98	103.92	-0.0529

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	104.71	104.79	104.88	0.088559	104.72	104.81	104.89	0.082434	0.0027	0.0209	0.044	0.021082
50	103.31	104.34	106.4	1.2013	102.9	104.42	106.31	1.227	-0.4107	0.0804	0.5635	0.38295
60	102.74	104.41	105.63	1.4258	102.73	104.43	105.56	1.5075	-0.2392	0.02858	0.3226	0.20822
100	102.77	103.54	105.08	0.92411	102.97	103.54	104.63	0.69298	-0.4528	0.00664	0.5306	0.36801
110	102.46	104.19	105.8	1.2559	102.63	104.13	105.3	1.1045	-0.4941	-0.0565	0.2089	0.27987

Device Test: 75.3 EXT_SET_FREQ_500KHZ(IntFreq|Freq/RT_90P9/7/7///90.9/634//1.8///@EXT_SET_FREQ_500KHZ)





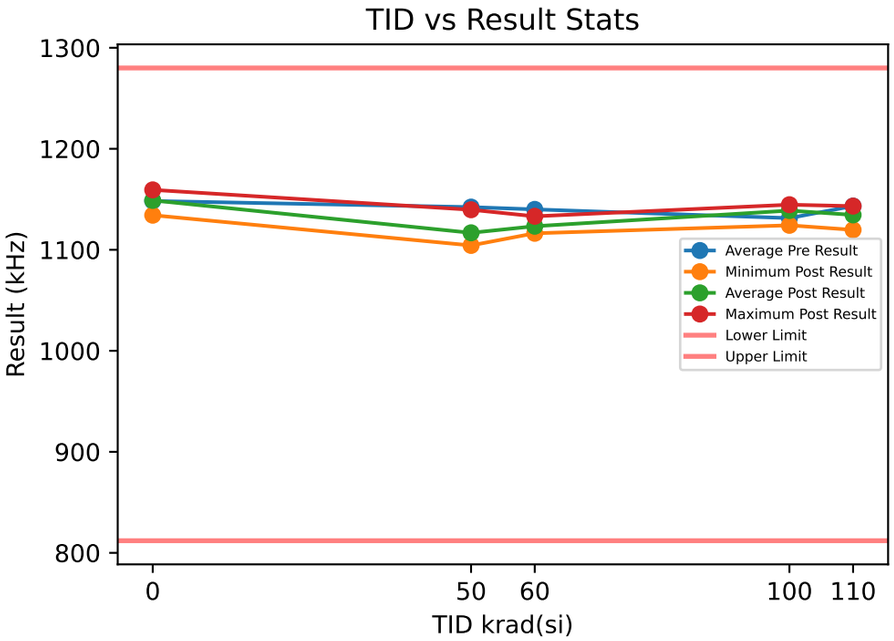
Test Results (Lower Limit = 446.0, Upper Limit = 564.0 (kHz))

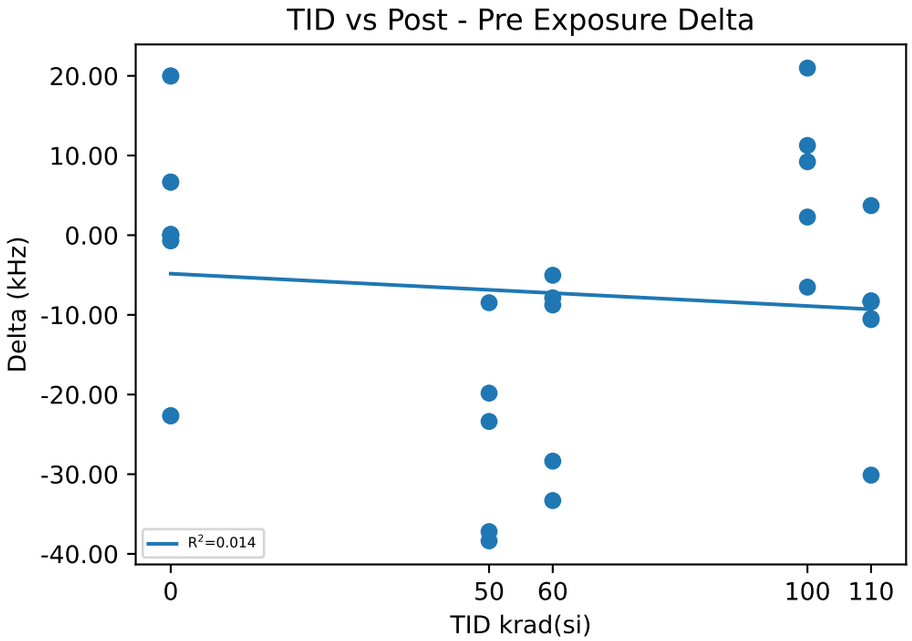
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	520.79	520.82	0.0332
2	0	CU2	515.13	514.85	-0.2776
3	0	CU3	518.96	518.62	-0.333
11	50	Unbiased-50k	510.55	508.22	-2.3314
12	50	Unbiased-50k	513.13	511.75	-1.3763
13	50	Unbiased-50k	513.24	512.8	-0.4377
14	50	Unbiased-50k	516.51	515.87	-0.6402
16	50	Unbiased-50k	524.41	522.32	-2.0877
17	60	Biased-50k	515.57	513.99	-1.5794
18	60	Biased-50k	519.37	517.99	-1.3776
19	60	Biased-50k	512.51	510.14	-2.3693
20	60	Biased-50k	518.68	517.65	-1.0255
21	60	Biased-50k	517.46	516.87	-0.5847
24	100	Unbiased-100k	514.8	513.59	-1.2071
25	100	Unbiased-100k	505.25	503.8	-1.453
26	100	Unbiased-100k	510.67	510.53	-0.1371
27	100	Unbiased-100k	511.18	511.64	0.4614
28	100	Unbiased-100k	519.02	516.96	-2.0598
29	110	Biased-100k	508.86	508.31	-0.5437
30	110	Biased-100k	525.5	523	-2.5028
31	110	Biased-100k	516.25	517.11	0.8608
32	110	Biased-100k	513.41	511.62	-1.7891
34	110	Biased-100k	516.38	515.59	-0.7847

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	515.13	518.29	520.79	2.8879	514.85	518.1	520.82	3.0196	-0.333	-0.19247	0.0332	0.19739
50	510.55	515.57	524.41	5.3738	508.22	514.19	522.32	5.3003	-2.3314	-1.3747	-0.4377	0.84278
60	512.51	516.72	519.37	2.7581	510.14	515.33	517.99	3.3003	-2.3693	-1.3873	-0.5847	0.66641
100	505.25	512.18	519.02	5.1216	503.8	511.3	516.96	4.8538	-2.0598	-0.87912	0.4614	1.0221
110	508.86	516.08	525.5	6.0876	508.31	515.13	523	5.5877	-2.5028	-0.9519	0.8608	1.2832

Device Test: 75.4 EXT_SET_FREQ_1000KHZ(IntFreq|Freq/RT37P4/7/7///90.9/634//1.8///@EXT_SET_FREQ_1000KHZ)





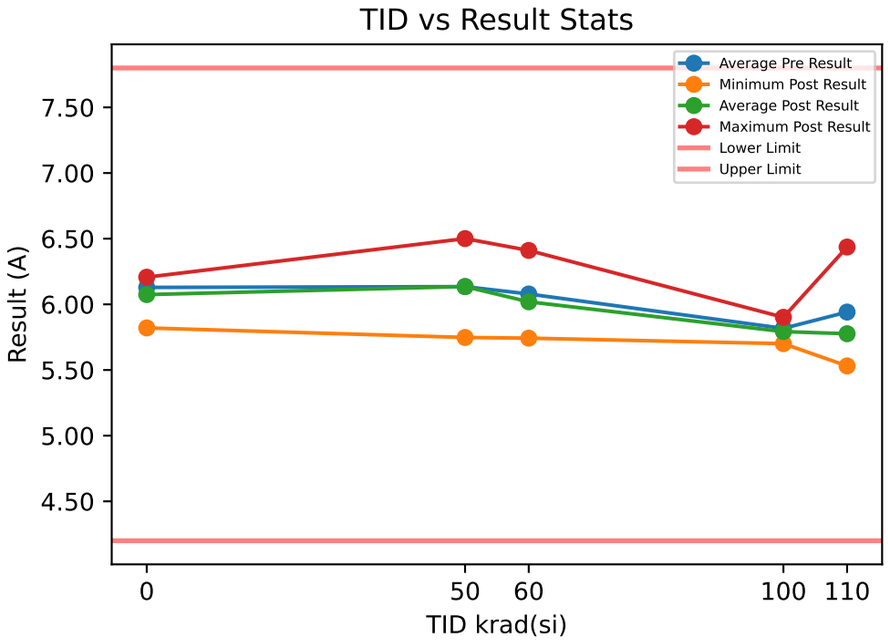
Test Results (Lower Limit = 812.0, Upper Limit = 1280.0 (kHz))

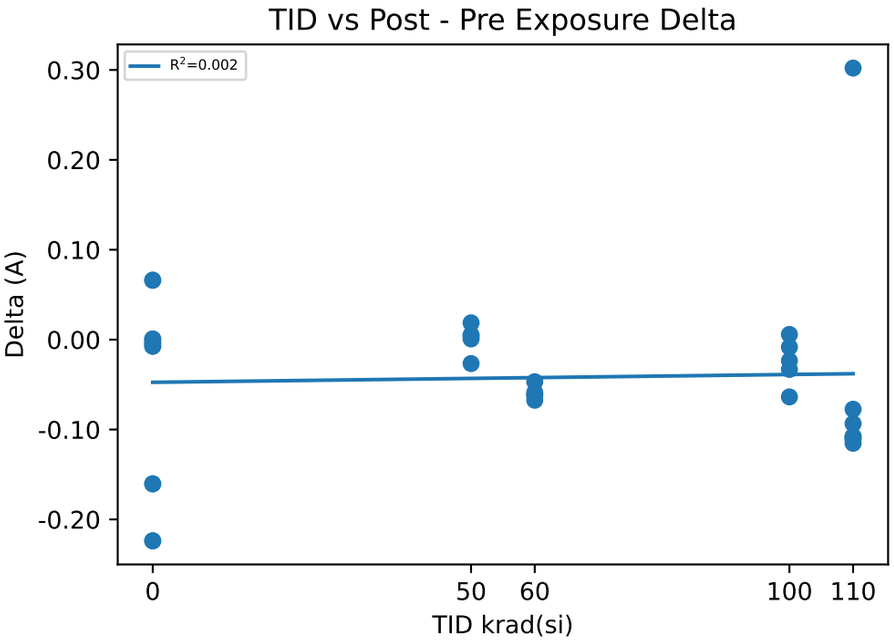
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	1152.7	1152.8	0.0917
2	0	CU2	1134.3	1134.2	-0.0428
3	0	CU3	1158	1157.3	-0.6904
11	50	Unbiased-50k	1140	1120.1	-19.825
12	50	Unbiased-50k	1143.4	1106.1	-37.206
13	50	Unbiased-50k	1142.7	1104.3	-38.362
14	50	Unbiased-50k	1137.2	1113.8	-23.38
16	50	Unbiased-50k	1148.1	1139.7	-8.4781
17	60	Biased-50k	1132.5	1127.5	-5.0292
18	60	Biased-50k	1147.4	1119.1	-28.359
19	60	Biased-50k	1128.5	1120.6	-7.8653
20	60	Biased-50k	1141.9	1133.2	-8.7591
21	60	Biased-50k	1149.7	1116.3	-33.311
24	100	Unbiased-100k	1139.2	1141.4	2.2779
25	100	Unbiased-100k	1103.3	1124.2	20.977
26	100	Unbiased-100k	1130.3	1141.6	11.265
27	100	Unbiased-100k	1133	1142.2	9.2172
28	100	Unbiased-100k	1151.2	1144.6	-6.5204
29	110	Biased-100k	1128.8	1132.6	3.7142
30	110	Biased-100k	1153.7	1143.2	-10.462
31	110	Biased-100k	1149.9	1119.7	-30.118
32	110	Biased-100k	1137.2	1126.6	-10.592
34	110	Biased-100k	1146.9	1138.6	-8.2572

Test Statistics (kHz)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1134.3	1148.3	1158	12.44	1134.2	1148.1	1157.3	12.217	-0.6904	-0.21383	0.0917	0.41816
50	1137.2	1142.3	1148.1	4.0846	1104.3	1116.8	1139.7	14.241	-38.362	-25.45	-8.4781	12.539
60	1128.5	1140	1149.7	9.2326	1116.3	1123.3	1133.2	6.8549	-33.311	-16.665	-5.0292	13.126
100	1103.3	1131.4	1151.2	17.648	1124.2	1138.8	1144.6	8.2493	-6.5204	7.4433	20.977	10.278
110	1128.8	1143.3	1153.7	10.135	1119.7	1132.1	1143.2	9.3542	-30.118	-11.143	3.7142	12.144

Device Test: 77.2 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW1/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





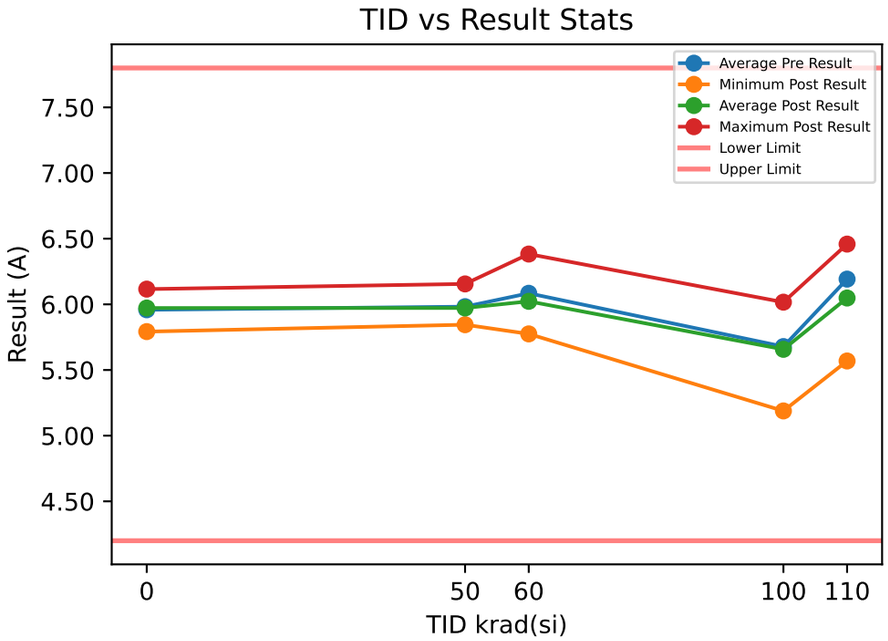
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

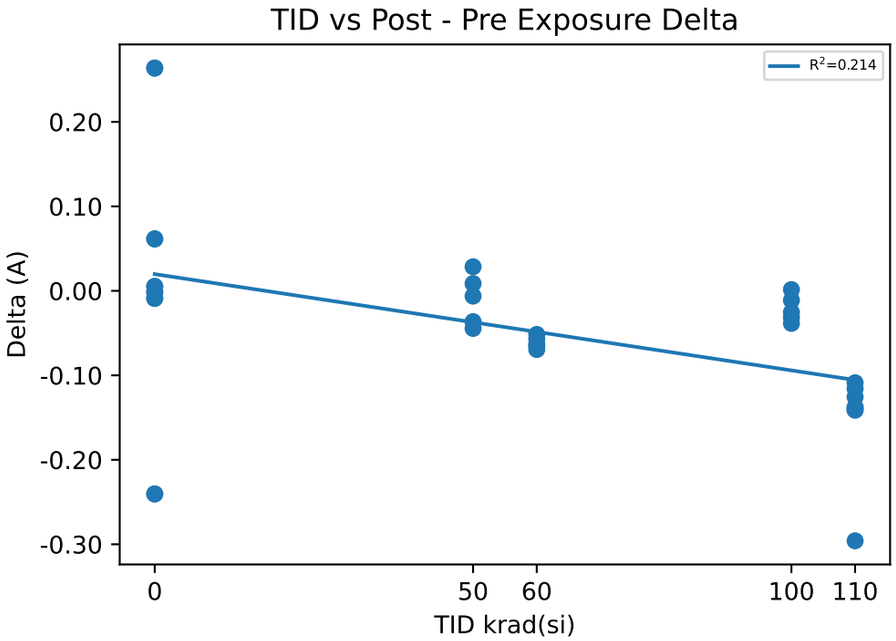
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0443	6.0409	-0.0034
2	0	CU2	6.2018	6.2025	0.0007
3	0	CU3	6.1406	6.1333	-0.0073
11	50	Unbiased-50k	5.7469	5.7477	0.0008
12	50	Unbiased-50k	6.0269	6.0456	0.0187
13	50	Unbiased-50k	6.1469	6.1203	-0.0266
14	50	Unbiased-50k	6.4969	6.5008	0.0039
16	50	Unbiased-50k	6.2571	6.2625	0.0054
17	60	Biased-50k	6.4732	6.4107	-0.0625
18	60	Biased-50k	6.0399	5.9725	-0.0674
19	60	Biased-50k	6.13	6.0832	-0.0468
20	60	Biased-50k	5.9471	5.8884	-0.0587
21	60	Biased-50k	5.8037	5.7426	-0.0611
24	100	Unbiased-100k	5.8721	5.839	-0.0331
25	100	Unbiased-100k	5.9096	5.9013	-0.0083
26	100	Unbiased-100k	5.6947	5.7005	0.0058
27	100	Unbiased-100k	5.8444	5.8209	-0.0235
28	100	Unbiased-100k	5.7642	5.7005	-0.0637
29	110	Biased-100k	5.6217	5.5443	-0.0774
30	110	Biased-100k	6.252	6.1586	-0.0934
31	110	Biased-100k	6.0569	5.9416	-0.1153
32	110	Biased-100k	6.1343	6.4364	0.3021
34	110	Biased-100k	5.6414	5.5309	-0.1105

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.0443	6.1289	6.2018	0.079399	6.0409	6.1256	6.2025	0.081077	-0.0073	-0.0033333	0.0007	0.0040004
50	5.7469	6.1349	6.4969	0.27764	5.7477	6.1354	6.5008	0.27761	-0.0266	0.00044	0.0187	0.016593
60	5.8037	6.0788	6.4732	0.25135	5.7426	6.0195	6.4107	0.25158	-0.0674	-0.0593	-0.0468	0.0076763
100	5.6947	5.817	5.9096	0.086756	5.7005	5.7924	5.9013	0.089071	-0.0637	-0.02456	0.0058	0.02642
110	5.6217	5.9413	6.252	0.29122	5.5309	5.9224	6.4364	0.39262	-0.1153	-0.0189	0.3021	0.18007

Device Test: 77.3 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW2/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





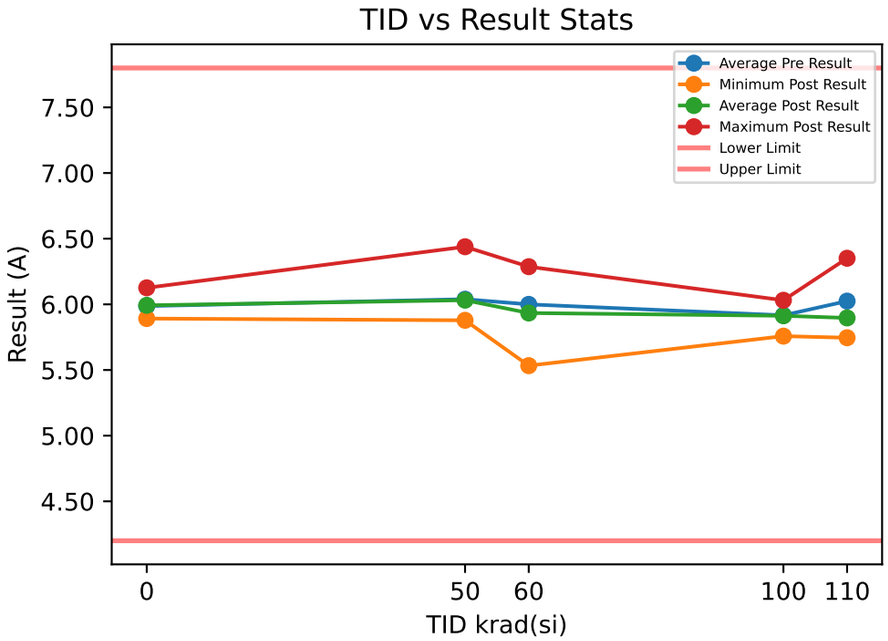
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

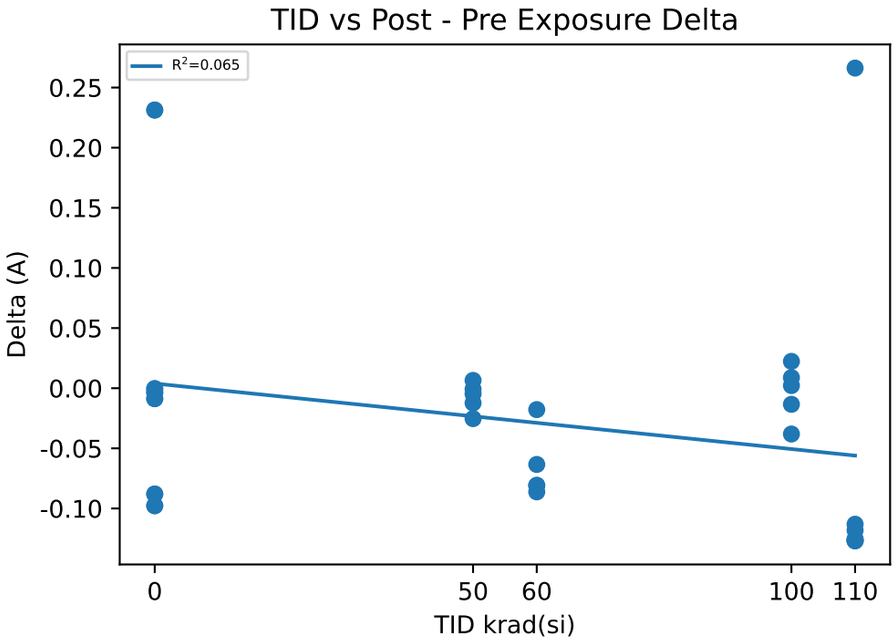
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	6.0545	6.0531	-0.0014
2	0	CU2	5.7872	5.7924	0.0052
3	0	CU3	6.0344	6.0255	-0.0089
11	50	Unbiased-50k	5.8164	5.8449	0.0285
12	50	Unbiased-50k	5.9546	5.9101	-0.0445
13	50	Unbiased-50k	6.1248	6.0883	-0.0365
14	50	Unbiased-50k	6.1469	6.1555	0.0086
16	50	Unbiased-50k	5.8689	5.8627	-0.0062
17	60	Biased-50k	6.115	6.0456	-0.0694
18	60	Biased-50k	6.0522	5.9887	-0.0635
19	60	Biased-50k	6.44	6.383	-0.057
20	60	Biased-50k	5.9874	5.9223	-0.0651
21	60	Biased-50k	5.8266	5.775	-0.0516
24	100	Unbiased-100k	5.6071	5.6086	0.0015
25	100	Unbiased-100k	5.737	5.7056	-0.0314
26	100	Unbiased-100k	6.0419	6.0166	-0.0253
27	100	Unbiased-100k	5.1995	5.1884	-0.0111
28	100	Unbiased-100k	5.8069	5.7684	-0.0385
29	110	Biased-100k	6.1596	6.0438	-0.1158
30	110	Biased-100k	6.5676	6.4588	-0.1088
31	110	Biased-100k	5.6943	5.5687	-0.1256
32	110	Biased-100k	6.3298	6.0339	-0.2959
34	110	Biased-100k	6.2097	6.0686	-0.1411

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7872	5.9587	6.0545	0.14886	5.7924	5.957	6.0531	0.14321	-0.0089	-0.0017	0.0052	0.0070548
50	5.8164	5.9823	6.1469	0.14879	5.8449	5.9723	6.1555	0.14065	-0.0445	-0.01002	0.0285	0.030558
60	5.8266	6.0842	6.44	0.22599	5.775	6.0229	6.383	0.22524	-0.0694	-0.06132	-0.0516	0.0070262
100	5.1995	5.6785	6.0419	0.31085	5.1884	5.6575	6.0166	0.30249	-0.0385	-0.02096	0.0015	0.016102
110	5.6943	6.1922	6.5676	0.31982	5.5687	6.0348	6.4588	0.31554	-0.2959	-0.15744	-0.1088	0.078345

Device Test: 77.4 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW3/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





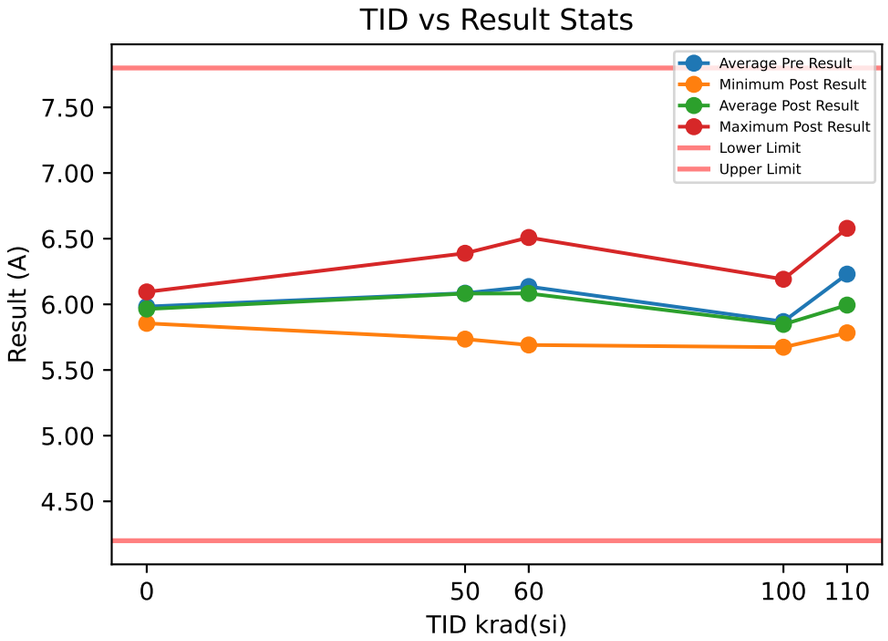
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

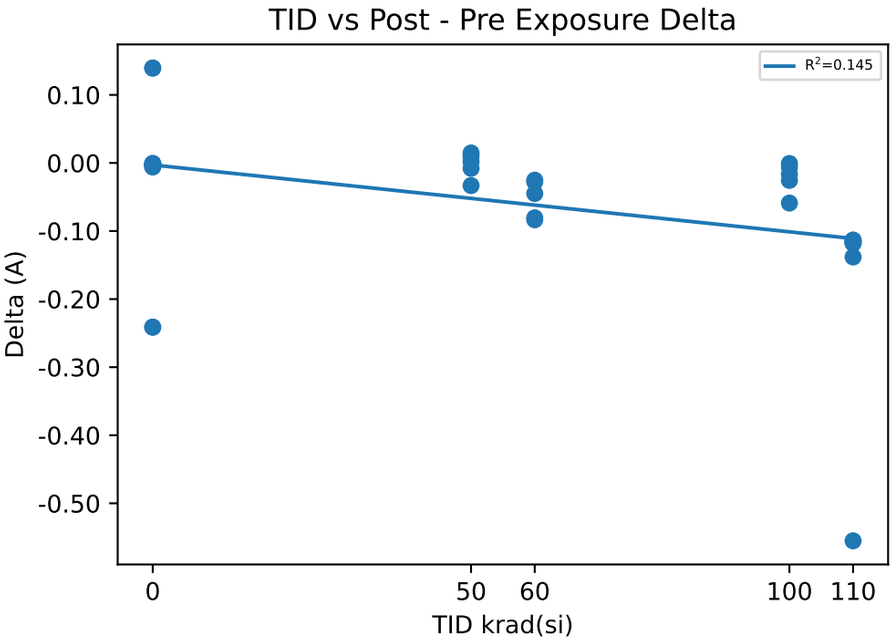
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.8946	5.8942	-0.0004
2	0	CU2	5.9895	5.9859	-0.0036
3	0	CU3	6.0769	6.0682	-0.0087
11	50	Unbiased-50k	5.9089	5.8966	-0.0123
12	50	Unbiased-50k	5.9037	5.8784	-0.0253
13	50	Unbiased-50k	5.8946	5.8938	-0.0008
14	50	Unbiased-50k	6.4322	6.4387	0.0065
16	50	Unbiased-50k	6.0559	6.0512	-0.0047
17	60	Biased-50k	6.0693	5.9883	-0.081
18	60	Biased-50k	6.0745	5.9883	-0.0862
19	60	Biased-50k	6.3046	6.2868	-0.0178
20	60	Biased-50k	5.9539	5.8732	-0.0807
21	60	Biased-50k	5.5966	5.5332	-0.0634
24	100	Unbiased-100k	5.9816	5.9435	-0.0381
25	100	Unbiased-100k	6.029	6.0312	0.0022
26	100	Unbiased-100k	5.7491	5.7579	0.0088
27	100	Unbiased-100k	5.8365	5.8231	-0.0134
28	100	Unbiased-100k	5.9867	6.009	0.0223
29	110	Biased-100k	5.929	5.8108	-0.1182
30	110	Biased-100k	6.3567	6.2436	-0.1131
31	110	Biased-100k	5.8709	5.7457	-0.1252
32	110	Biased-100k	6.0848	6.351	0.2662
34	110	Biased-100k	5.882	5.7555	-0.1265

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8946	5.987	6.0769	0.091176	5.8942	5.9828	6.0682	0.087042	-0.0087	-0.0042333	-0.0004	0.0041861
50	5.8946	6.0391	6.4322	0.22966	5.8784	6.0317	6.4387	0.23812	-0.0253	-0.00732	0.0065	0.012129
60	5.5966	5.9998	6.3046	0.25884	5.5332	5.934	6.2868	0.27143	-0.0862	-0.06582	-0.0178	0.028191
100	5.7491	5.9166	6.029	0.11858	5.7579	5.9129	6.0312	0.11859	-0.0381	-0.00364	0.0223	0.023154
110	5.8709	6.0247	6.3567	0.20434	5.7457	5.9813	6.351	0.29199	-0.1265	-0.04336	0.2662	0.17313

Device Test: 77.5 LOW_SIDE_OC_SOURCE(ILIM_LS|LS_Sourcing/SW4/5/5///90.9/634//1.8///@LOW_SIDE_OC_SOURCE





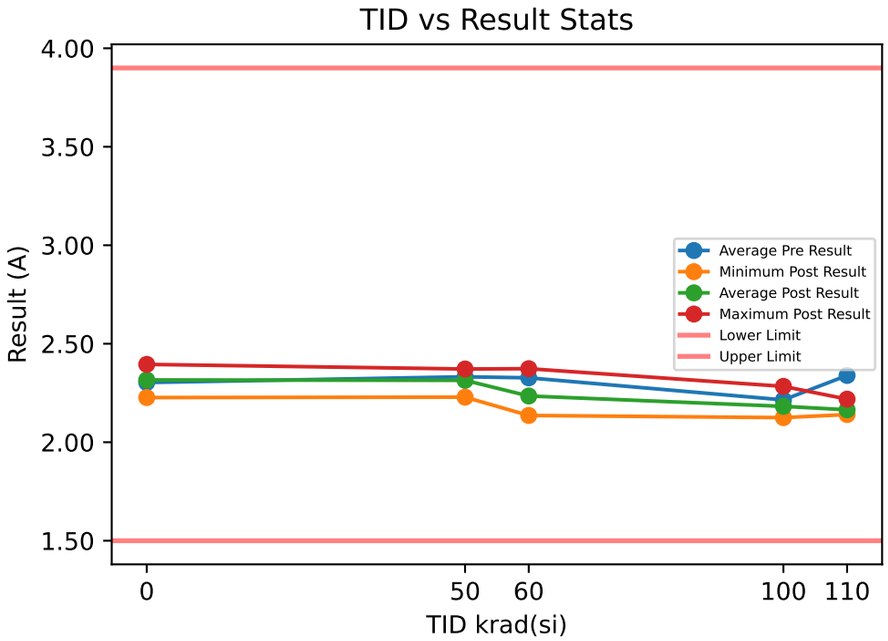
Test Results (Lower Limit = 4.2, Upper Limit = 7.8 (A))

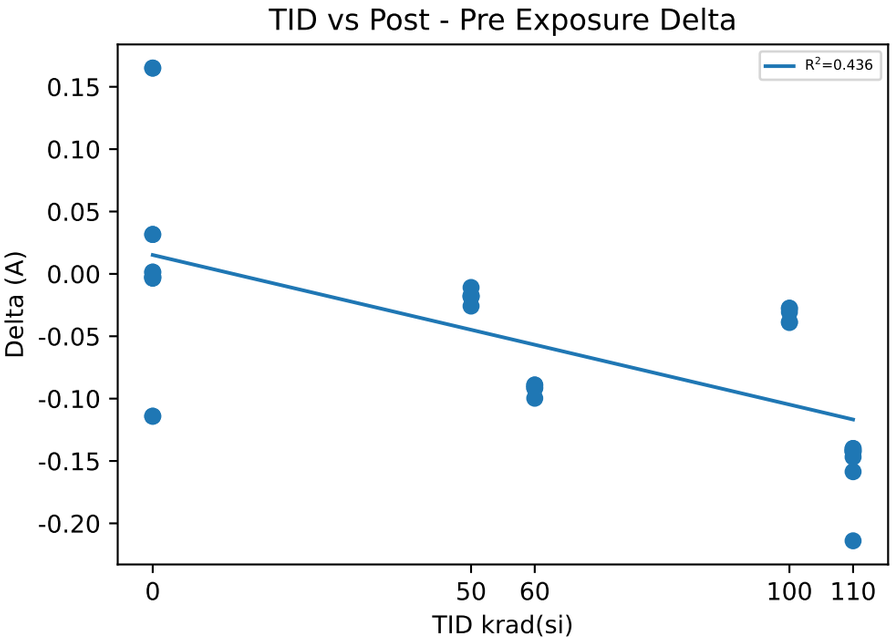
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	5.9942	5.9934	-0.0008
2	0	CU2	5.8586	5.8558	-0.0028
3	0	CU3	6.0966	6.0947	-0.0019
11	50	Unbiased-50k	5.7258	5.7352	0.0094
12	50	Unbiased-50k	5.8689	5.861	-0.0079
13	50	Unbiased-50k	6.3872	6.3889	0.0017
14	50	Unbiased-50k	6.3271	6.3418	0.0147
16	50	Unbiased-50k	6.1168	6.0836	-0.0332
17	60	Biased-50k	6.0089	5.9836	-0.0253
18	60	Biased-50k	6.3267	6.2461	-0.0806
19	60	Biased-50k	6.554	6.5091	-0.0449
20	60	Biased-50k	6.069	5.9855	-0.0835
21	60	Biased-50k	5.7183	5.6906	-0.0277
24	100	Unbiased-100k	6.197	6.1911	-0.0059
25	100	Unbiased-100k	5.6899	5.6734	-0.0165
26	100	Unbiased-100k	5.8393	5.8385	-0.0008
27	100	Unbiased-100k	5.7563	5.7307	-0.0256
28	100	Unbiased-100k	5.8618	5.8029	-0.0589
29	110	Biased-100k	6.0563	5.9182	-0.1381
30	110	Biased-100k	6.692	6.5788	-0.1132
31	110	Biased-100k	5.897	5.7832	-0.1138
32	110	Biased-100k	6.4417	5.8866	-0.5551
34	110	Biased-100k	6.0638	5.9459	-0.1179

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8586	5.9831	6.0966	0.11939	5.8558	5.9813	6.0947	0.11991	-0.0028	-0.0018333	-0.0008	0.0010017
50	5.7258	6.0852	6.3872	0.28578	5.7352	6.0821	6.3889	0.28757	-0.0332	-0.00306	0.0147	0.018876
60	5.7183	6.1354	6.554	0.31867	5.6906	6.083	6.5091	0.30884	-0.0835	-0.0524	-0.0253	0.028121
100	5.6899	5.8689	6.197	0.19577	5.6734	5.8473	6.1911	0.20254	-0.0589	-0.02154	-0.0008	0.02298
110	5.897	6.2302	6.692	0.3267	5.7832	6.0225	6.5788	0.317	-0.5551	-0.20762	-0.1132	0.19451

Device Test: 77.6 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW1/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK)





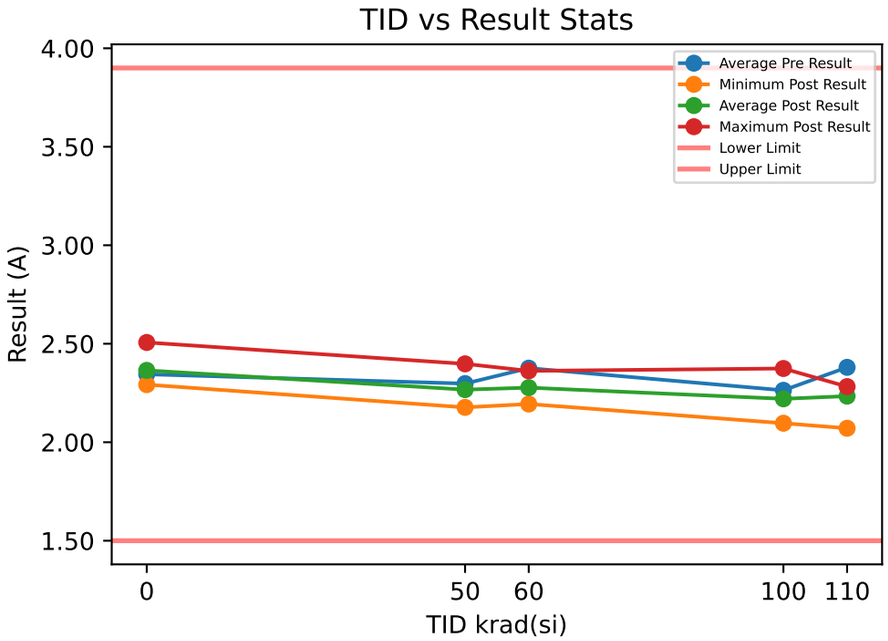
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

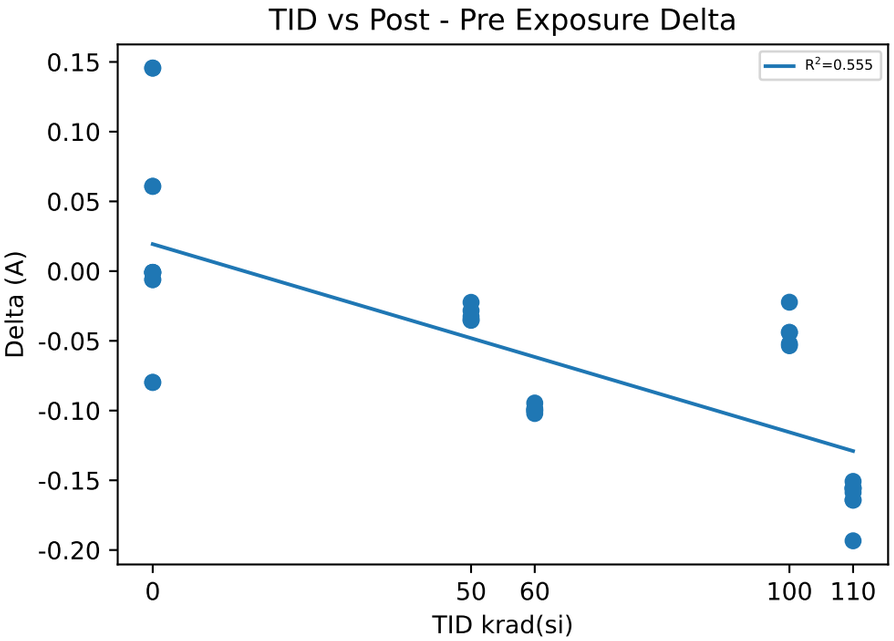
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.2827	2.2841	0.0014
2	0	CU2	2.3965	2.3943	-0.0022
3	0	CU3	2.2302	2.2268	-0.0034
11	50	Unbiased-50k	2.246	2.2288	-0.0172
12	50	Unbiased-50k	2.323	2.3046	-0.0184
13	50	Unbiased-50k	2.3475	2.3366	-0.0109
14	50	Unbiased-50k	2.3471	2.3291	-0.018
16	50	Unbiased-50k	2.3976	2.3718	-0.0258
17	60	Biased-50k	2.4648	2.3734	-0.0914
18	60	Biased-50k	2.3115	2.2118	-0.0997
19	60	Biased-50k	2.3499	2.2608	-0.0891
20	60	Biased-50k	2.2835	2.192	-0.0915
21	60	Biased-50k	2.225	2.1359	-0.0891
24	100	Unbiased-100k	2.3226	2.2836	-0.039
25	100	Unbiased-100k	2.2175	2.1869	-0.0306
26	100	Unbiased-100k	2.163	2.1356	-0.0274
27	100	Unbiased-100k	2.1634	2.1249	-0.0385
28	100	Unbiased-100k	2.2077	2.1798	-0.0279
29	110	Biased-100k	2.3104	2.1636	-0.1468
30	110	Biased-100k	2.3546	2.2129	-0.1417
31	110	Biased-100k	2.3143	2.1557	-0.1586
32	110	Biased-100k	2.4328	2.2188	-0.214
34	110	Biased-100k	2.2831	2.1407	-0.1424

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2302	2.3031	2.3965	0.085012	2.2268	2.3017	2.3943	0.085131	-0.0034	-0.0014	0.0014	0.002498
50	2.246	2.3322	2.3976	0.055336	2.2288	2.3142	2.3718	0.053448	-0.0258	-0.01806	-0.0109	0.0052923
60	2.225	2.3269	2.4648	0.089512	2.1359	2.2348	2.3734	0.089482	-0.0997	-0.09216	-0.0891	0.0043758
100	2.163	2.2148	2.3226	0.065199	2.1249	2.1822	2.2836	0.062779	-0.039	-0.03268	-0.0274	0.005676
110	2.2831	2.339	2.4328	0.058298	2.1407	2.1783	2.2188	0.035278	-0.214	-0.1607	-0.1417	0.030555

Device Test: 77.7 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW2/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK)





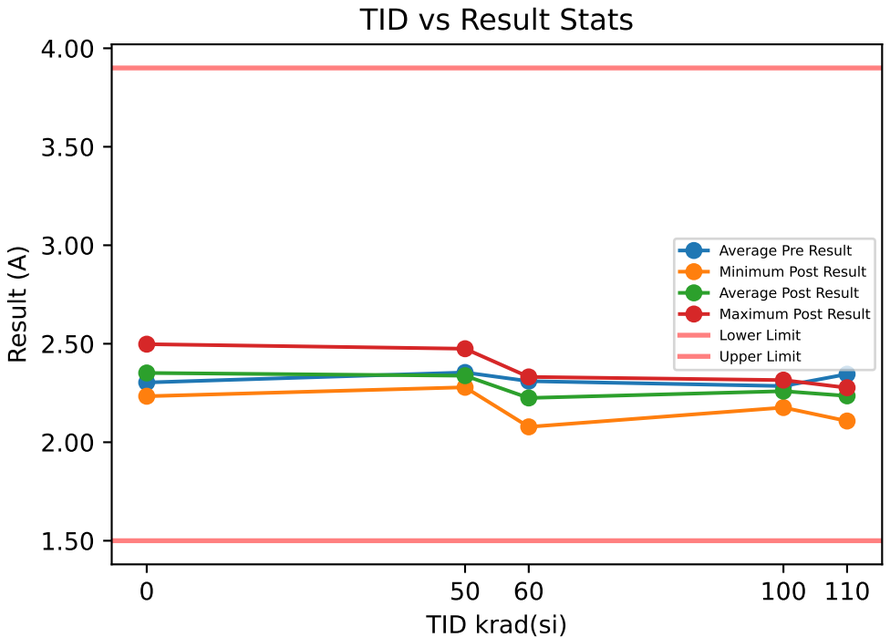
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

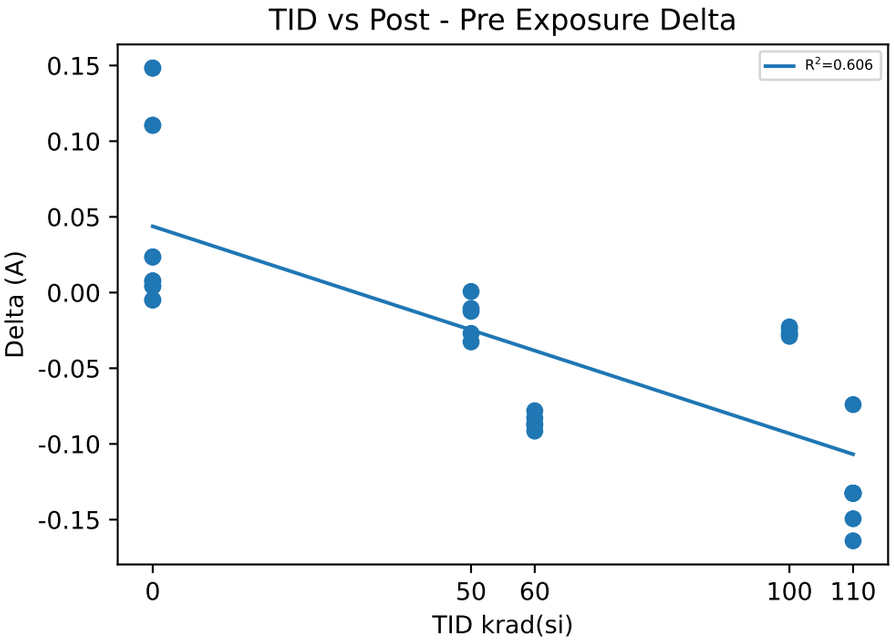
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3609	2.36	-0.0009
2	0	CU2	2.2934	2.2924	-0.001
3	0	CU3	2.3807	2.3746	-0.0061
11	50	Unbiased-50k	2.2053	2.177	-0.0283
12	50	Unbiased-50k	2.3214	2.2865	-0.0349
13	50	Unbiased-50k	2.2665	2.2339	-0.0326
14	50	Unbiased-50k	2.4332	2.3979	-0.0353
16	50	Unbiased-50k	2.2622	2.2398	-0.0224
17	60	Biased-50k	2.2886	2.194	-0.0946
18	60	Biased-50k	2.462	2.3623	-0.0997
19	60	Biased-50k	2.4241	2.322	-0.1021
20	60	Biased-50k	2.4012	2.3011	-0.1001
21	60	Biased-50k	2.3044	2.2059	-0.0985
24	100	Unbiased-100k	2.199	2.1455	-0.0535
25	100	Unbiased-100k	2.2017	2.1794	-0.0223
26	100	Unbiased-100k	2.3585	2.3064	-0.0521
27	100	Unbiased-100k	2.1405	2.0965	-0.044
28	100	Unbiased-100k	2.4182	2.3743	-0.0439
29	110	Biased-100k	2.3716	2.2129	-0.1587
30	110	Biased-100k	2.4036	2.2528	-0.1508
31	110	Biased-100k	2.227	2.0709	-0.1561
32	110	Biased-100k	2.4758	2.2824	-0.1934
34	110	Biased-100k	2.4229	2.2587	-0.1642

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2934	2.345	2.3807	0.04577	2.2924	2.3423	2.3746	0.043855	-0.0061	-0.0026667	-0.0009	0.0029738
50	2.2053	2.2977	2.4332	0.086159	2.177	2.267	2.3979	0.082841	-0.0353	-0.0307	-0.0224	0.0054097
60	2.2886	2.3761	2.462	0.07601	2.194	2.2771	2.3623	0.073868	-0.1021	-0.099	-0.0946	0.0027803
100	2.1405	2.2636	2.4182	0.11839	2.0965	2.2204	2.3743	0.11589	-0.0535	-0.04316	-0.0223	0.012482
110	2.227	2.3802	2.4758	0.093614	2.0709	2.2155	2.2824	0.08463	-0.1934	-0.16464	-0.1508	0.016786

Device Test: 77.8 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW3/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK)





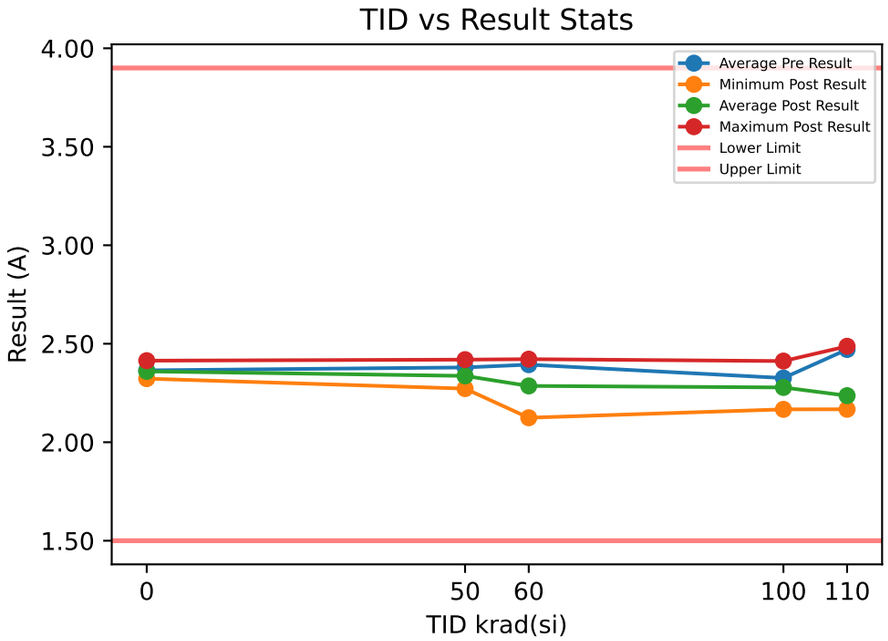
Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

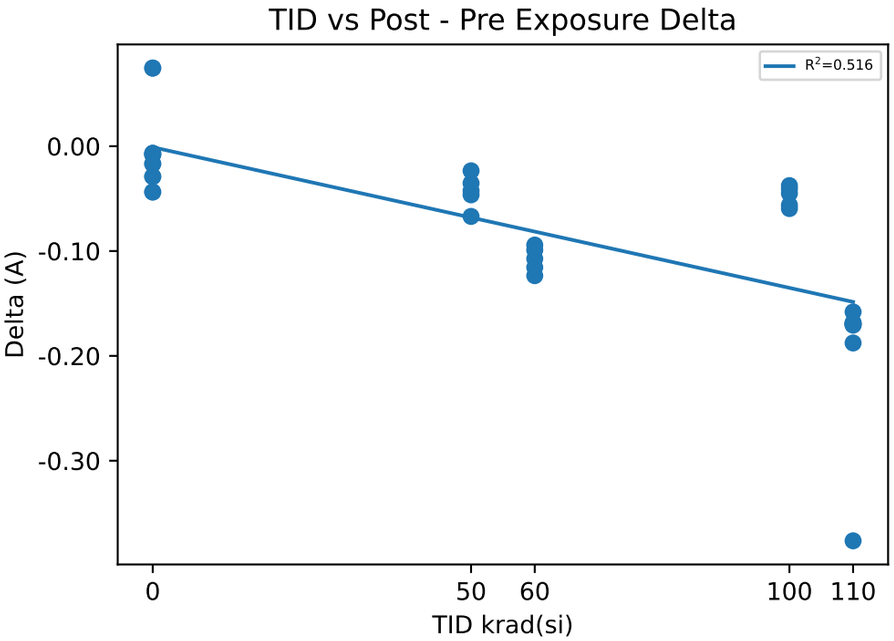
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3495	2.3572	0.0077
2	0	CU2	2.3313	2.3264	-0.0049
3	0	CU3	2.2293	2.2335	0.0042
11	50	Unbiased-50k	2.2894	2.2789	-0.0105
12	50	Unbiased-50k	2.3507	2.3181	-0.0326
13	50	Unbiased-50k	2.3424	2.33	-0.0124
14	50	Unbiased-50k	2.474	2.4747	0.0007
16	50	Unbiased-50k	2.3139	2.2869	-0.027
17	60	Biased-50k	2.3052	2.2271	-0.0781
18	60	Biased-50k	2.3072	2.2204	-0.0868
19	60	Biased-50k	2.4191	2.3315	-0.0876
20	60	Biased-50k	2.3582	2.2667	-0.0915
21	60	Biased-50k	2.1609	2.0781	-0.0828
24	100	Unbiased-100k	2.2001	2.176	-0.0241
25	100	Unbiased-100k	2.3345	2.3118	-0.0227
26	100	Unbiased-100k	2.2811	2.2545	-0.0266
27	100	Unbiased-100k	2.2673	2.2384	-0.0289
28	100	Unbiased-100k	2.3432	2.3154	-0.0278
29	110	Biased-100k	2.3467	2.1827	-0.164
30	110	Biased-100k	2.3882	2.2388	-0.1494
31	110	Biased-100k	2.2404	2.1077	-0.1327
32	110	Biased-100k	2.3507	2.2767	-0.074
34	110	Biased-100k	2.4017	2.2692	-0.1325

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.2293	2.3034	2.3495	0.064786	2.2335	2.3057	2.3572	0.064396	-0.0049	0.0023333	0.0077	0.0065041
50	2.2894	2.3541	2.474	0.071286	2.2789	2.3377	2.4747	0.079452	-0.0326	-0.01636	0.0007	0.013398
60	2.1609	2.3101	2.4191	0.095509	2.0781	2.2248	2.3315	0.093121	-0.0915	-0.08536	-0.0781	0.0051003
100	2.2001	2.2852	2.3432	0.057822	2.176	2.2592	2.3154	0.057668	-0.0289	-0.02602	-0.0227	0.0025743
110	2.2404	2.3455	2.4017	0.063357	2.1077	2.215	2.2767	0.070476	-0.164	-0.13052	-0.074	0.034207

Device Test: 77.9 LOW_SIDE_OC_SINK(ILIM_LS|LS_Sinking/SW4/5/5///90.9/634//1.8///@LOW_SIDE_OC_SINK)





Test Results (Lower Limit = 1.5, Upper Limit = 3.9 (A))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	CU1	2.3396	2.3228	-0.0168
2	0	CU2	2.3677	2.3596	-0.0081
3	0	CU3	2.3874	2.3806	-0.0068
11	50	Unbiased-50k	2.2957	2.2722	-0.0235
12	50	Unbiased-50k	2.3444	2.2774	-0.067
13	50	Unbiased-50k	2.4029	2.3604	-0.0425
14	50	Unbiased-50k	2.4009	2.3545	-0.0464
16	50	Unbiased-50k	2.4546	2.4193	-0.0353
17	60	Biased-50k	2.4337	2.3394	-0.0943
18	60	Biased-50k	2.529	2.4217	-0.1073
19	60	Biased-50k	2.529	2.4055	-0.1235
20	60	Biased-50k	2.2538	2.1382	-0.1156
21	60	Biased-50k	2.2234	2.1243	-0.0991
24	100	Unbiased-100k	2.4716	2.4121	-0.0595
25	100	Unbiased-100k	2.3847	2.3438	-0.0409
26	100	Unbiased-100k	2.3123	2.2561	-0.0562
27	100	Unbiased-100k	2.2491	2.2115	-0.0376
28	100	Unbiased-100k	2.2119	2.1669	-0.045
29	110	Biased-100k	2.338	2.1673	-0.1707
30	110	Biased-100k	2.6748	2.4871	-0.1877
31	110	Biased-100k	2.3957	2.2376	-0.1581
32	110	Biased-100k	2.5768	2.2004	-0.3764
34	110	Biased-100k	2.3689	2.1989	-0.17

Test Statistics (A)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3396	2.3649	2.3874	0.024023	2.3228	2.3543	2.3806	0.029258	-0.0168	-0.010567	-0.0068	0.0054372
50	2.2957	2.3797	2.4546	0.061032	2.2722	2.3368	2.4193	0.062004	-0.067	-0.04294	-0.0235	0.016026
60	2.2234	2.3938	2.529	0.1473	2.1243	2.2858	2.4217	0.14451	-0.1235	-0.10796	-0.0943	0.011889
100	2.2119	2.3259	2.4716	0.1046	2.1669	2.2781	2.4121	0.099445	-0.0595	-0.04784	-0.0376	0.0095777
110	2.338	2.4708	2.6748	0.14706	2.1673	2.2583	2.4871	0.13033	-0.3764	-0.21258	-0.1581	0.092183

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